Radiation Report

SN55LVCP22A-SP Total Ionizing Dose (TID) Lookahead Radiation Report

ABSTRACT

This report discusses the results of the Total Ionizing Dose (TID) testing for the QML Class V RHA certified Texas Instruments (TI) SN55LVCP22A-SP (5962R1124201VFA). The study was done to determine total ionizing dose (TID) effects under low dose rate (LDR) up to 100 krad(Si) and high dose rate (HDR) up to 50 krad(Si) without anneal and 100 krad(Si) with anneal. The results show that all samples passed within the specified limits up to 100 krad(Si).

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1 Device Information

1.1 Product Description

The SN55LVCP22A-SP is a 2×2 crosspoint switch providing up to 1-Gbps operation for each path. The dual channels incorporate wide, common-mode receivers (0 V to 4 V), allowing for the receipt of LVDS, LVPECL, and CML signals. The dual outputs are LVDS drivers to provide low-power, low-EMI, high-speed operation. The SN55LVCP22A-SP provides a single device supporting 2:2 buffering (repeating), 1:2 splitting, 2:1 multiplexing, 2×2 switching, and LVPECL/CML to LVDS level translation on each channel. The flexible operation of the SN55LVCP22A-SP provides a single device to support the redundant serial bus transmission needs (working and protection switching cards) of fault-tolerant switch systems found in optical networking, wireless infrastructure, and data communications systems. The SN55LVCP22A-SP uses a fully differential data path to ensure low-noise generation, fast switching times, low-pulse width distortion, and low jitter.

The 2×2 crosspoint switch features of the SN55LVCP22A-SP make it ideally suited for high-speed operation applications in next-generation spacecraft. The strong immunity to single event latch-up and total ionizing dose, enable the device to be used in a variety of space and radiation environments. It has been RHA qualified to 100 krad(Si) under both LDR and HDR.

1.2 Device Details

Table 1-1 lists the device information used in the initial TID characterization and qualification of LDR and HDR tests.

Table 1-1. Device and Exposure Details

TID LDR and HDR Details: 100 krad(Si)	
TI Device Number	SN55LVCP22A-SP
Package	16-pin W
Technology	RFBC1-8
Die Lot Number	9261232
A/T Lot Number / Date Code	0002831 / 2016A
Quantity Tested	84 irradiated devices + 3 control
Lot Accept/Reject	Devices passed 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)
HDR Radiation Facility	Texas Instruments SVA Group, Santa Clara, CA
LDR Radiation Facility	VPT Rad, Chelmsford, MA
HDR Dose Level	10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si), 150 krad(Si)
HDR Dose Rate	65 rad(Si)/s
LDR Dose Level	10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)
LDR Dose Rate	0.01 rad(Si)/s
HDR Radiation Source	Gamma cell 220 Excel (GC-220E) Co-60
LDR Radiation Source	Gamma cell Co-60 (JLS-81-22)
Irradiation Temperature	Ambient, room temperature

Figure 1-1. SN55LVCP22A-SP Device Used in Exposure

Table 1-2. Symbolization Table

Device Information	From SN55LVCP22A-SP Image (Figure 1-1)
Year, Quarter, Die Revision, and FAB Code	9D-R
Date Code	2016A
Device	5962-112401VFA
GPN	LVCP22W-SP
Bottom Marking	THA Q 086 TI Logo

2 Total Dose Test Setup

2.1 Test Overview

The SN55LVCP22A-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Condition A. The product was irradiated up to 100 krad(Si) and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The device was functional up to 100 krad(Si) and passed all electrical parametric tests with readings within guard bands of the data sheet electrical specification limits after 504 hours of anneal. The SN55LVCP22A-SP BICMOS process technology contains Bipolar and CMOS components. Both LDR and HDR tests were performed.

2.2 Test Description and Facilities

The SN55LVCP22A-SP LDR exposure was performed on biased and unbiased devices in a Co60 gamma cell under a 10-mrad(Si)/s exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10 mrad(Si)/s to a maximum of approximately 84 rad(Si)/s, determined by the distance from the source. For the LDR exposure (10 mrad(Si)/s), the test box was positioned approximately 2 m from the source.

The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry was verified using TLDs prior to the radiation exposures. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a post-radiation electrical evaluation using Texas Instruments production ATE. ATE test limits are set per SMD electrical limits based on initial qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

The SN55LVCP22A-SP HDR exposure was performed on biased and unbiased devices in a Co60 gamma cell at TI SVA facility in Santa Clara, California. The un-attenuated dose rate of this cell is 65 rad(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post-radiation electrical evaluation using Texas Instruments ATE. ATE test limits are set per SMD electrical limits based on initial qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removal of the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under LDR and HDR exposure were irradiated in both biased and unbiased conditions. Both conditions are described as follows.

1. **Unbiased** - - *For the unbiased conditions, the exposure was performed with all pins grounded.*
2. **Biased** - - *Figure 2-1 shows the diagram for LDR and HDR exposure with biased condition.*

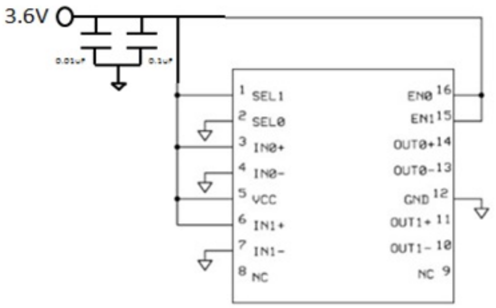


Figure 2-1. Bias Diagram Used in TID Exposure

2.4 Test Configuration and Condition

A step-stress (10k, 30k, 50k, and 100k) test method was used to determine the TID hardness level. That is, after a predetermined TID level was reached, an electrical test was performed on a given sample of parts to verify that the units are within specified data sheet electrical test limits. MIL-STD-883, Test Method 1019.9, Condition A was used in this case. If this passes, then the wafer lot can be certified as an RHA wafer lot.

Table 2-1. LDR = 10-mrad(Si)/s Biased and Unbiased Device Information

Total Samples: 10/dose level (5 biased + 5 unbiased)			
Exposure Level:			
10 krad(Si)	**30 krad(Si)**	**50 krad(Si)**	**100 krad(Si)**
Biased	**Biased**	**Biased**	**Biased**
001, 005, 007, 011, 015	001, 005, 007, 011, 015	001, 005, 007, 011, 015	003, 008, 012, 013, 016
(Wafer 1)	(Wafer 1)	(Wafer 1)	(Wafer 1)
Unbiased	**Unbiased**	**Unbiased**	**Unbiased**
006, 007, 008, 009, 010	006, 007, 008, 009, 010	006, 007, 008, 009, 010	011, 012, 013, 014, 015
(Wafer 1)	(Wafer 1)	(Wafer 1)	(Wafer 1)

Table 2-2. HDR = 65-rad(Si)/s Biased and Unbiased Device Information

Total Samples: 10/dose level (5 biased + 5 unbiased)			
Exposure Level:			
10 krad(Si)	**30 krad(Si)**	**50 krad(Si)**	**100 krad(Si)**
Biased	**Biased**	**Biased**	**Biased**
001, 002, 003, 004, 005	001, 002, 003, 004, 005	011, 012, 013, 014, 015	022 to 044
(Wafer 1)	(Wafer 1)	(Wafer 1)	(Wafer 1)
Unbiased	**Unbiased**	**Unbiased**	**Unbiased**
006, 007, 008, 009, 010	006, 007, 008, 009, 010	016, 017, 018, 019, 020	043 to 064
(Wafer 1)	(Wafer 1)	(Wafer 1)	(Wafer 1)

3 Specification Compliance Matrix (Electrical Characteristics)

Table 3-1. Tested Parameters

PARAMETER	TEST CONDITION	Data sheet Lit# SLLSFI8 – APRIL 2020 – REVISED DECEMBER 2020				Test# or Name
		MIN	TYP	MAX	UNIT	
High-level input current	VIN = 3.6 V or 2.0 V, VCC = 3.6 V	–25	±3	25	µA	IIH_36
Low-level input current	VIN = 0.0 V or 0.8 V, VCC = 3.6 V	–15	±1	15	µA	IIL_36
Input clamp voltage	ICL = –18 mA		–0.8	–1.5	V	VCL_30
Differential output voltage	RL = 75 Ω, VCC = 3.3 V, TA = 25°C	320	390	430	mV	VODH, VODL
Change in differential output voltage magnitude between logic states	VID = ±100 mV	–25		25	mV	DVOD
Steady-state offset voltage		1	1.2	1.45	V	VOSH/VOSL
Change in steady-state offset voltage between logic states		–25		25	mV	DVOS
High-impedance output current	VOUT = GND or VCC	–120		350	µA	IOZH_36,IOZL_36
Power-off leakage current	VCC = 0 V, 1.5 V; VOUT = 3.6 V or GND	–50		150	µA	IOFFH, IOFFL
Output short-circuit current	VOUT+ or VOUT- = 0 V			8	mA	IOSH_36, IOSL_36
Both outputs short-circuit current	VOUT+ and VOUT- = 0 V	–8		8	mA	IOSB_36
Positive-going differential input voltage threshold				100	mV	VIDH
Negative-going differential input voltage threshold		–100			mV	VIDL
Differential input voltage hysteresis			25	150	mV	VIDHYS
Input current	VIN = 4 V, VCC = 3.6 V or 0.0	–18	±1	18	µA	IIH_36
	VIN = 0 V, VCC = 3.6 V or 0.0	–18	±1	18		IIL_36
Quiescent supply current	RL = 75 Ω, EN0 = EN1 = High		60	87	mA	ICCH_36/ICCL_36
3-state supply current	EN0 = EN1 = Low		25	35	mA	ICCZH_36/ICCZL_36

4 Total Ionizing Dose Characterization Test Results

4.1 Total Ionizing Dose RHA Characterization Summary Result

The parametric data for the SN55LVCP22A-SP passes up to 100-krad(Si) LDR/HDR per MIL-STD-883, TM1090 Condition A. The SN55LVCP22A-SP passed post electrical test over all conditions listed below indicating that this lot can be certified as 30-krad(Si) RHA.

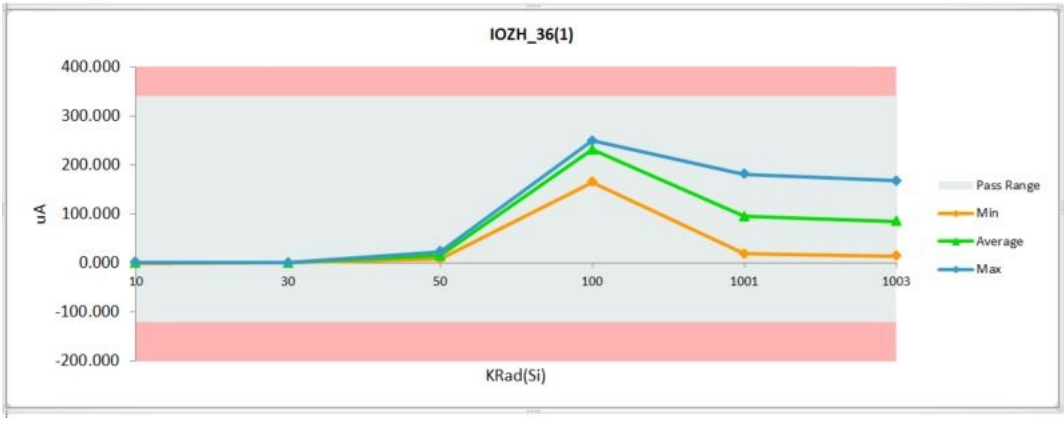
- LDR (0.01 rad(Si)/s) unbiased: Post 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)
- LDR (0.01 rad(Si)/s) biased: Post 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)
- HDR (100 rad(Si)/s) unbiased: Post 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)
- HDR (100 rad(Si)/s) biased: Post 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si)

Overall radiation performance was very solid. There were no functional or parametric failures at any read point. All data sheet parameters passed at all exposure levels with margin and ELDRS free. Critical Parameters for SN55LVCP22A-SP such as high-impedance output current (IOZ) and power-off leakage current (IOFF) were still within specifications.

Note: HDR has passed up to 100 krad(Si)/s under biased anneal (after 480 hours of anneal). The biased anneal devices are labeled "1001" for 1 week anneal and "1003" for 3 week anneal in the data in order to create separation between the time 0 (T0) 100 krad(Si)/s and 3 weeks anneal.

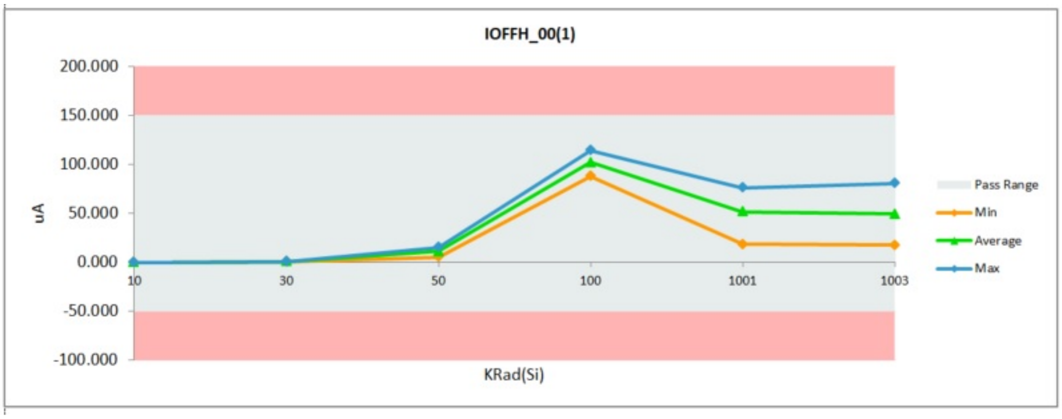
1. High-impedance output current (IOZ)

High-impedance output current exhibits an increase from 50 krad(Si) to 100 krad(Si). Amount of shift from 50 krad(Si) to 100 krad(Si) was 206 μA. The IOZH parameter is within the specifications.



2. Power-off leakage current (IOFF)

Power-off leakage current exhibits an increase from 50 krad(Si) to 100 krad(Si). Amount of shift from 50 krad(Si) to 100 krad(Si) was 96.2 μA. The IOFF parameter is within the specifications.



5 Applicable and Reference Documents

5.1 Applicable Documents

- *SN55LVCP22A-SP Class V 2x2 LVDS Crosspoint Switch* data sheet

5.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

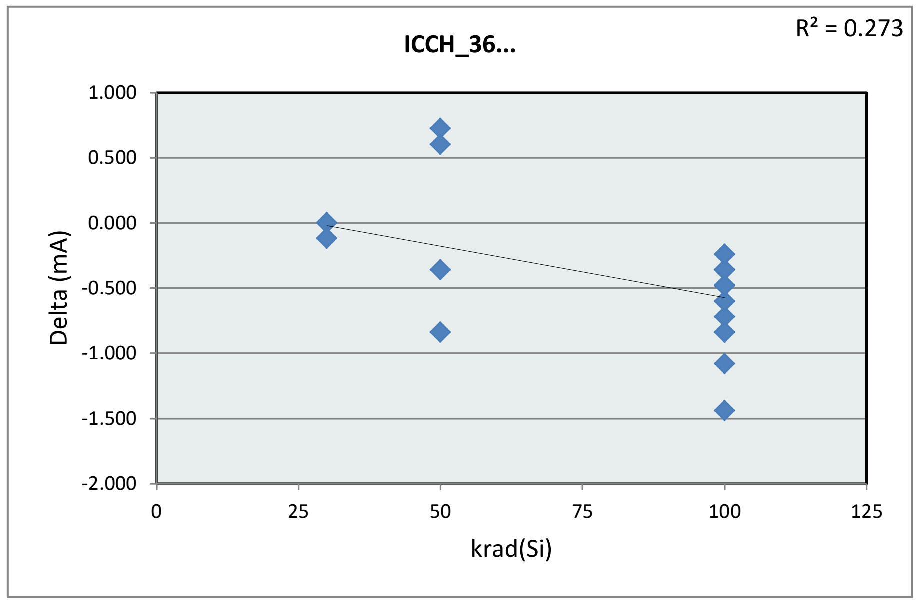
A Appendix A: TID Data

This appendix provides the SN55LVCP22-SP TID HDR and LDR report.

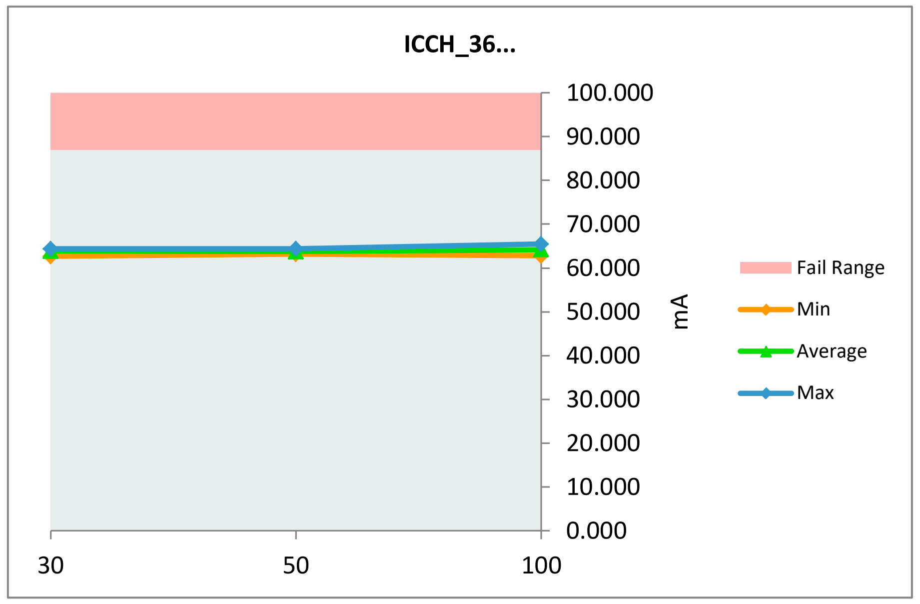
HDR TID Report T0 data
SN55LVCP22A-SP

	ICCH_36...	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	87	87
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	63.997	64.116	-0.119
30	2	62.676	62.675	0.001
30	3	64.357	64.356	0.001
30	4	64.117	64.116	0.001
30	5	63.877	63.996	-0.119
50	11	63.157	63.996	-0.839
50	12	63.877	63.155	0.722
50	13	64.357	63.756	0.601
50	14	62.556	63.395	-0.839
50	15	63.997	64.356	-0.359
100	22	63.277	64.117	-0.840
100	23	62.797	63.517	-0.720
100	24	63.277	63.877	-0.600
100	25	64.117	64.718	-0.601
100	26	63.997	64.357	-0.360
100	27	63.997	64.357	-0.360
100	28	64.117	64.598	-0.481
100	29	64.117	64.478	-0.361
100	30	63.877	64.237	-0.360
100	31	63.517	63.997	-0.480
100	32	63.277	63.637	-0.360
100	33	62.556	62.797	-0.241
100	34	63.997	65.438	-1.441
100	35	63.877	64.958	-1.081
100	36	63.997	64.838	-0.841
100	37	63.637	64.478	-0.841
100	38	63.277	64.117	-0.840
100	39	63.517	64.117	-0.600
100	40	63.397	63.877	-0.480
100	41	63.157	63.637	-0.480
100	42	63.637	63.997	-0.360
100	43	63.997	64.237	-0.240
100	44	63.997	64.237	-0.240
	Max	64.357	65.438	0.722
	Average	63.648	64.077	-0.429
	Min	62.556	62.675	-1.441
	Std Dev	0.508	0.571	0.430



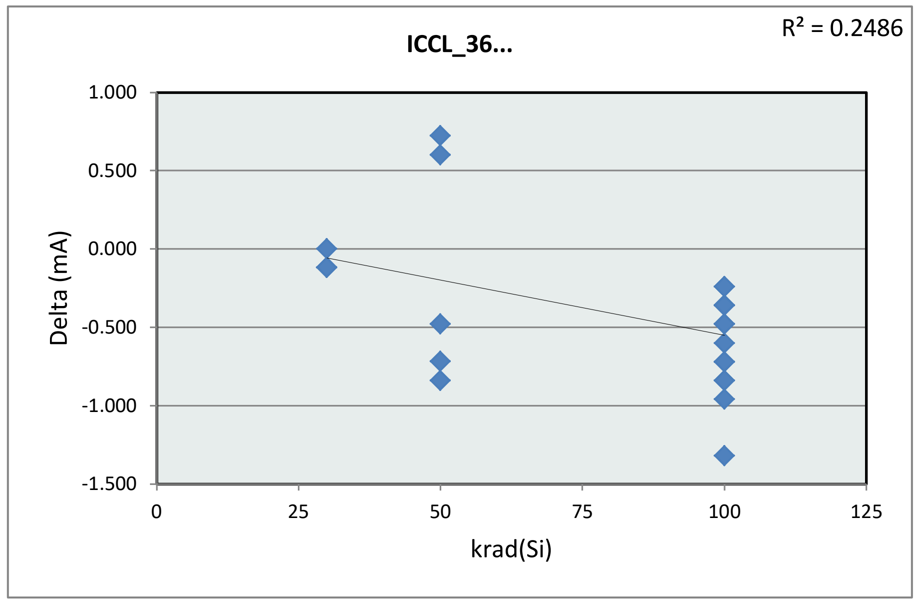
	ICCH_36...		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	87	mA	
Min Limit		mA	
krad(Si)	30	50	100
LL			
Min	62.675	63.155	62.797
Average	63.852	63.732	64.201
Max	64.356	64.356	65.438
UL	87.000	87.000	87.000



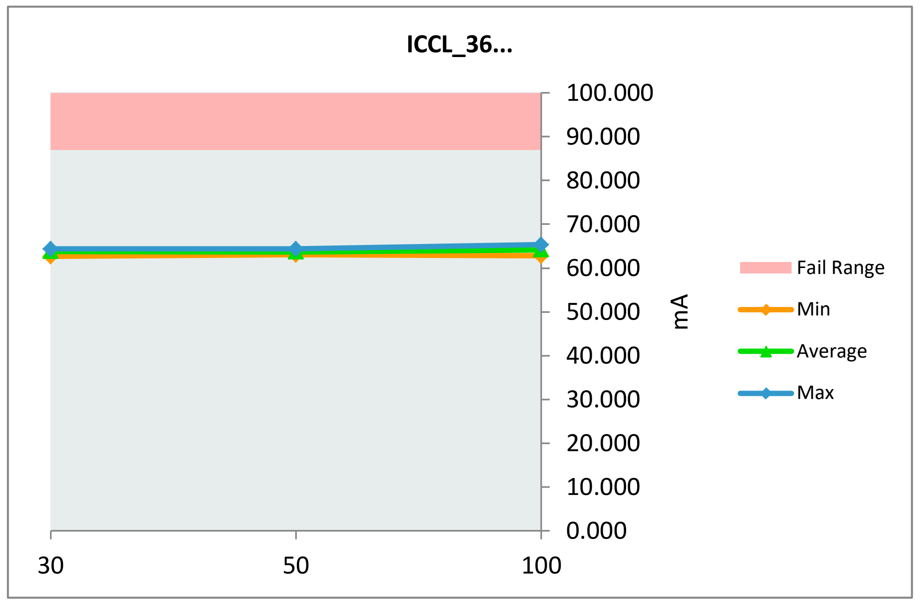
HDR TID Report T0 data
SN55LVCP22A-SP

	ICCL_36...	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	87	87
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	63.877	63.996	-0.119
30	2	62.556	62.675	-0.119
30	3	64.237	64.356	-0.119
30	4	63.997	64.116	-0.119
30	5	63.877	63.876	0.001
50	11	63.157	63.996	-0.839
50	12	63.757	63.035	0.722
50	13	64.357	63.756	0.601
50	14	62.556	63.275	-0.719
50	15	63.877	64.356	-0.479
100	22	63.277	63.997	-0.720
100	23	62.676	63.517	-0.841
100	24	63.277	63.757	-0.480
100	25	64.117	64.718	-0.601
100	26	63.997	64.237	-0.240
100	27	63.997	64.237	-0.240
100	28	64.117	64.478	-0.361
100	29	63.997	64.478	-0.481
100	30	63.877	64.237	-0.360
100	31	63.517	63.997	-0.480
100	32	63.277	63.637	-0.360
100	33	62.556	62.797	-0.241
100	34	63.997	65.318	-1.321
100	35	63.877	64.838	-0.961
100	36	63.997	64.718	-0.721
100	37	63.637	64.478	-0.841
100	38	63.277	64.117	-0.840
100	39	63.397	64.117	-0.720
100	40	63.397	63.757	-0.360
100	41	63.157	63.637	-0.480
100	42	63.517	63.877	-0.360
100	43	63.877	64.237	-0.360
100	44	63.877	64.237	-0.360
	Max	64.357	65.318	0.722
	Average	63.604	64.026	-0.422
	Min	62.556	62.675	-1.321
	Std Dev	0.502	0.561	0.404

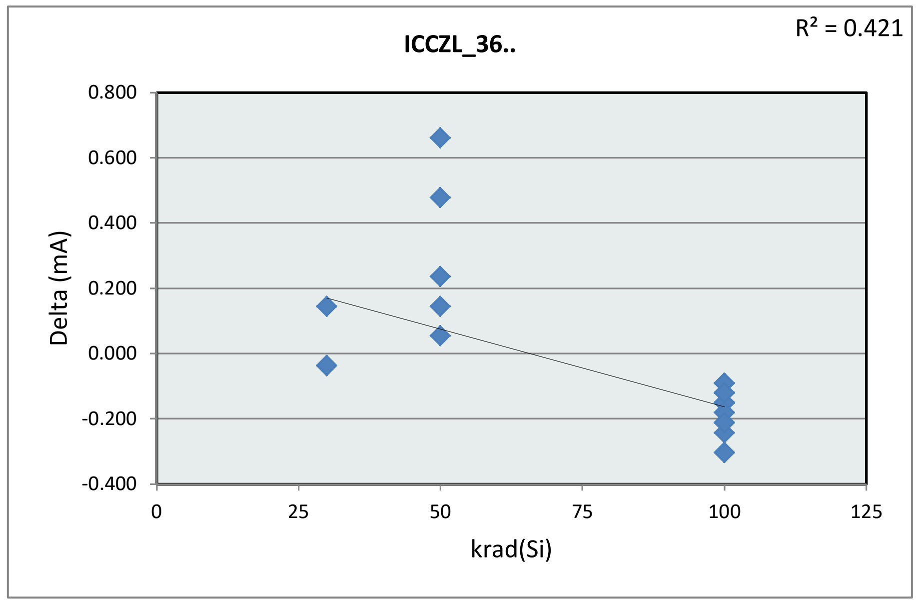


	ICCL_36...		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	87	mA	
Min Limit		mA	
krad(Si)	30	50	100
LL			
Min	62.675	63.035	62.797
Average	63.804	63.684	64.149
Max	64.356	64.356	65.318
UL	87.000	87.000	87.000

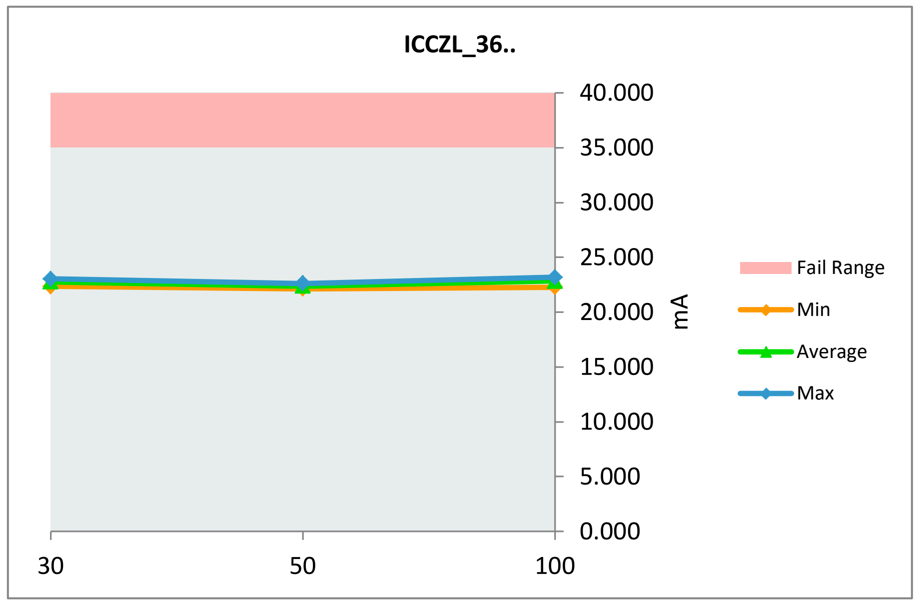


HDR TID Report T0 data
SN55LVCP22A-SP

		ICCZL_36..		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	35	35	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	22.791	22.829	-0.038
30	2	22.305	22.343	-0.038
30	3	23.003	23.041	-0.038
30	4	22.912	22.950	-0.038
30	5	22.821	22.677	0.144
50	11	22.518	22.464	0.054
50	12	22.821	22.161	0.660
50	13	22.973	22.495	0.478
50	14	22.275	22.131	0.144
50	15	22.851	22.616	0.236
100	22	22.586	22.798	-0.212
100	23	22.282	22.495	-0.213
100	24	22.495	22.738	-0.243
100	25	22.829	22.950	-0.121
100	26	22.768	22.859	-0.091
100	27	22.829	22.981	-0.152
100	28	22.768	22.889	-0.121
100	29	22.768	22.859	-0.091
100	30	22.829	22.981	-0.152
100	31	22.647	22.798	-0.151
100	32	22.464	22.616	-0.152
100	33	22.191	22.282	-0.091
100	34	22.798	23.102	-0.304
100	35	22.798	23.102	-0.304
100	36	22.889	23.193	-0.304
100	37	22.707	22.920	-0.213
100	38	22.434	22.586	-0.152
100	39	22.647	22.859	-0.212
100	40	22.616	22.798	-0.182
100	41	22.495	22.677	-0.182
100	42	22.707	22.920	-0.213
100	43	22.829	22.950	-0.121
100	44	22.829	22.950	-0.121
	Max	23.003	23.193	0.660
	Average	22.681	22.758	-0.077
	Min	22.191	22.131	-0.304
	Std Dev	0.213	0.269	0.209



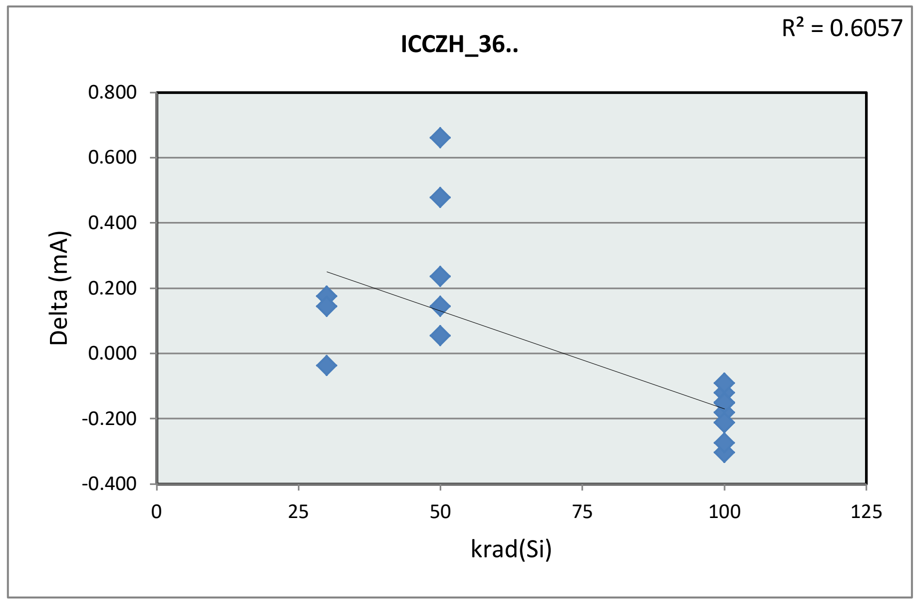
	ICCZL_36..		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	35	mA	
Min Limit		mA	
krad(Si)	30	50	100
LL			
Min	22.343	22.131	22.282
Average	22.768	22.373	22.839
Max	23.041	22.616	23.193
UL	35.000	35.000	35.000



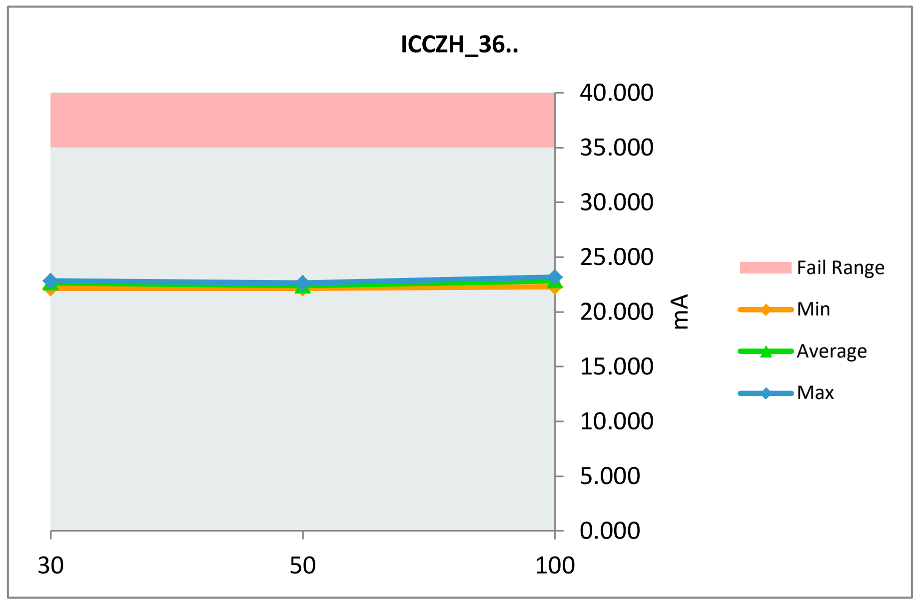
HDR TID Report T0 data
SN55LVCP22A-SP

	ICCZH_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	22.791	22.829	-0.038
30	2	22.305	22.131	0.174
30	3	23.003	22.829	0.174
30	4	22.912	22.768	0.144
30	5	22.821	22.677	0.144
50	11	22.518	22.464	0.054
50	12	22.821	22.161	0.660
50	13	22.973	22.495	0.478
50	14	22.275	22.131	0.144
50	15	22.851	22.616	0.236
100	22	22.586	22.798	-0.212
100	23	22.313	22.495	-0.182
100	24	22.495	22.707	-0.212
100	25	22.798	22.950	-0.152
100	26	22.768	22.859	-0.091
100	27	22.829	22.981	-0.152
100	28	22.768	22.889	-0.121
100	29	22.768	22.889	-0.121
100	30	22.829	22.981	-0.152
100	31	22.647	22.798	-0.151
100	32	22.464	22.616	-0.152
100	33	22.191	22.282	-0.091
100	34	22.798	23.102	-0.304
100	35	22.798	23.102	-0.304
100	36	22.889	23.163	-0.274
100	37	22.707	22.920	-0.213
100	38	22.434	22.616	-0.182
100	39	22.616	22.829	-0.213
100	40	22.616	22.798	-0.182
100	41	22.495	22.677	-0.182
100	42	22.707	22.920	-0.213
100	43	22.798	22.950	-0.152
100	44	22.798	22.950	-0.152
	Max	23.003	23.163	0.660
	Average	22.678	22.739	-0.060
	Min	22.191	22.131	-0.304
	Std Dev	0.210	0.273	0.220

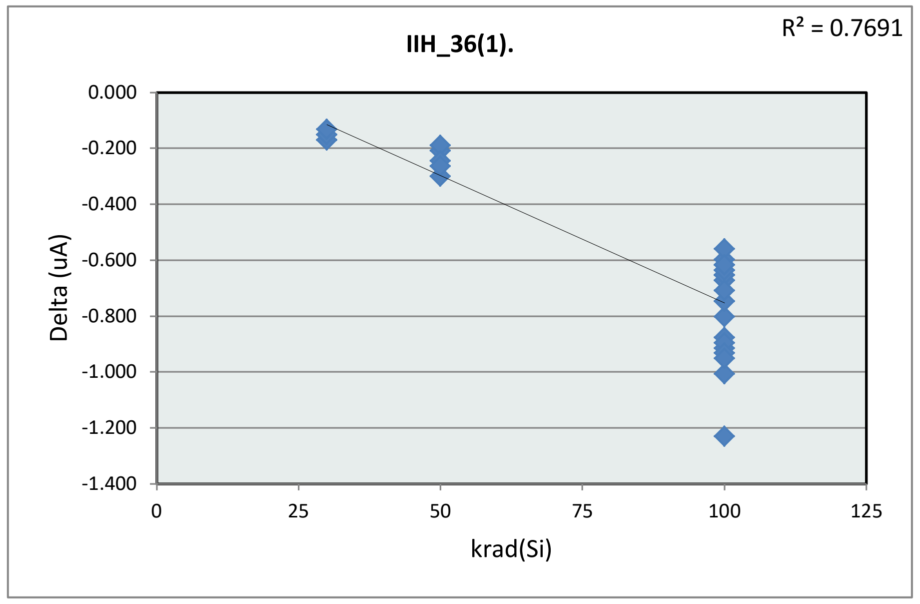


	ICCZH_36..		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	35	mA	
Min Limit		mA	
krad(Si)	30	50	100
LL			
Min	22.131	22.131	22.282
Average	22.647	22.373	22.838
Max	22.829	22.616	23.163
UL	35.000	35.000	35.000

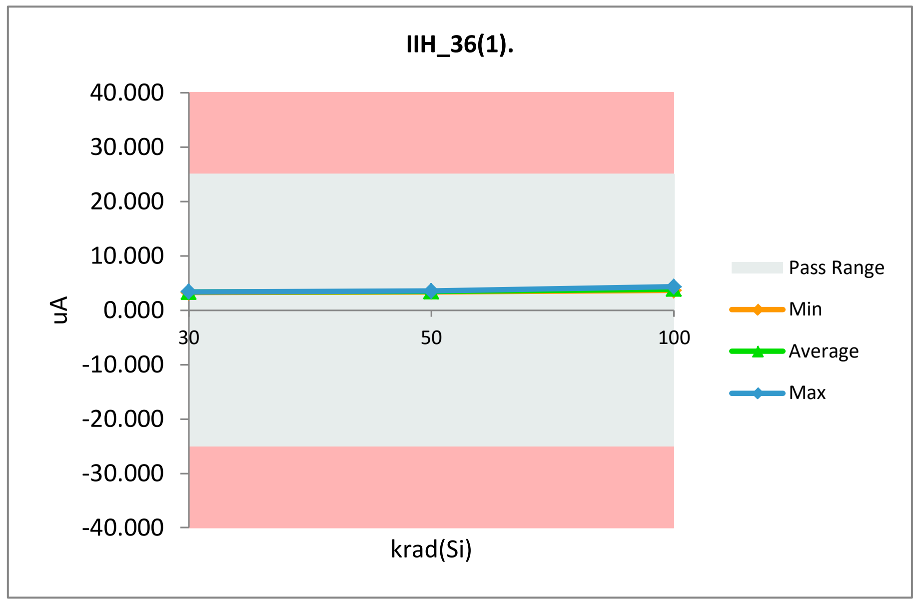


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	3.162	3.314	-0.152
30	2	3.237	3.407	-0.170
30	3	3.162	3.333	-0.171
30	4	3.106	3.258	-0.152
30	5	3.125	3.258	-0.133
50	11	3.237	3.445	-0.208
50	12	3.143	3.445	-0.302
50	13	3.181	3.370	-0.189
50	14	3.274	3.519	-0.245
50	15	3.143	3.407	-0.264
100	22	3.155	4.032	-0.877
100	23	3.229	4.144	-0.915
100	24	3.211	4.014	-0.803
100	25	3.080	3.828	-0.748
100	26	3.155	3.828	-0.673
100	27	3.099	3.753	-0.654
100	28	3.099	3.772	-0.673
100	29	3.155	3.809	-0.654
100	30	3.024	3.641	-0.617
100	31	3.136	3.772	-0.636
100	32	3.211	3.809	-0.598
100	33	3.285	3.846	-0.561
100	34	3.099	4.330	-1.231
100	35	3.062	4.070	-1.008
100	36	3.117	4.014	-0.897
100	37	3.099	4.032	-0.933
100	38	3.341	4.293	-0.952
100	39	3.099	3.846	-0.747
100	40	3.043	3.697	-0.654
100	41	3.155	3.865	-0.710
100	42	3.080	3.716	-0.636
100	43	3.099	3.716	-0.617
100	44	3.099	3.716	-0.617
	Max	3.341	4.330	-0.133
	Average	3.149	3.736	-0.588
	Min	3.024	3.258	-1.231
	Std Dev	0.072	0.291	0.297

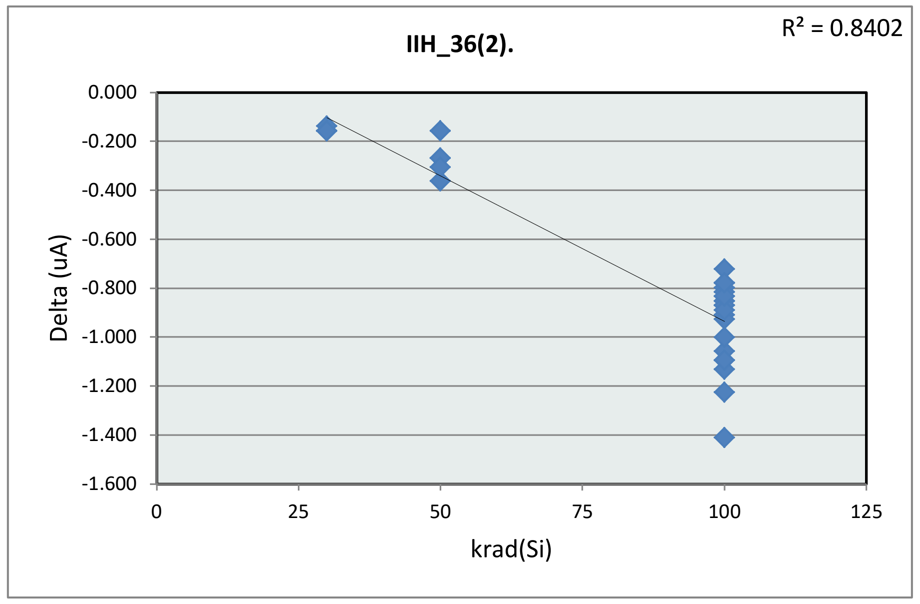


	IIH_36(1).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.258	3.370	3.641
Average	3.314	3.437	3.893
Max	3.407	3.519	4.330
UL	25.000	25.000	25.000

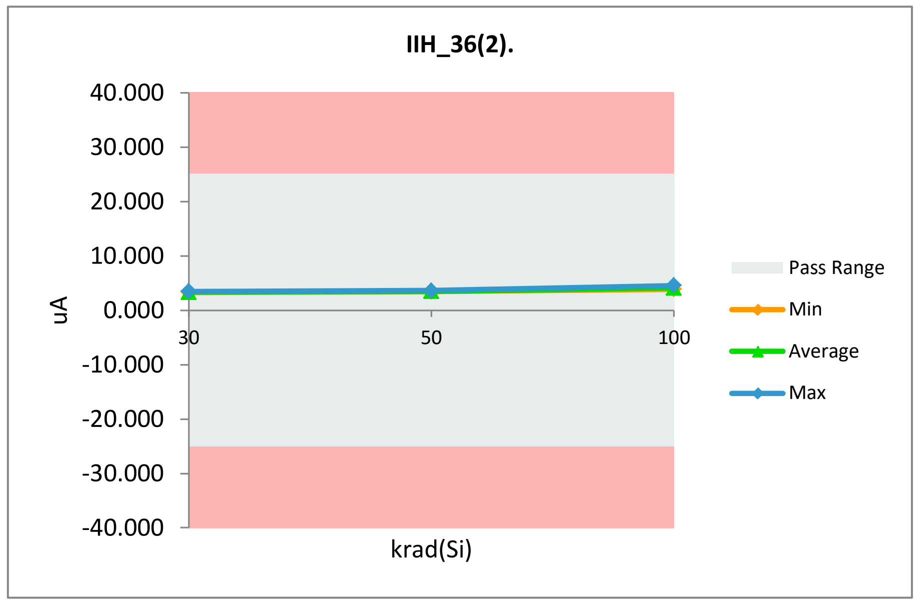


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	3.182	3.321	-0.139
30	2	3.312	3.470	-0.158
30	3	3.163	3.321	-0.158
30	4	3.107	3.265	-0.158
30	5	3.126	3.284	-0.158
50	11	3.275	3.432	-0.157
50	12	3.163	3.525	-0.362
50	13	3.163	3.432	-0.269
50	14	3.349	3.618	-0.269
50	15	3.126	3.432	-0.306
100	22	3.220	4.277	-1.057
100	23	3.294	4.389	-1.095
100	24	3.276	4.277	-1.001
100	25	3.127	4.036	-0.909
100	26	3.220	4.073	-0.853
100	27	3.109	3.961	-0.852
100	28	3.109	3.980	-0.871
100	29	3.183	4.054	-0.871
100	30	3.071	3.869	-0.798
100	31	3.164	3.980	-0.816
100	32	3.276	4.054	-0.778
100	33	3.369	4.092	-0.723
100	34	3.146	4.556	-1.410
100	35	3.090	4.315	-1.225
100	36	3.090	4.184	-1.094
100	37	3.127	4.259	-1.132
100	38	3.424	4.519	-1.095
100	39	3.146	4.073	-0.927
100	40	3.090	3.924	-0.834
100	41	3.201	4.092	-0.891
100	42	3.090	3.924	-0.834
100	43	3.146	3.924	-0.778
100	44	3.146	3.924	-0.778
	Max	3.424	4.556	-0.139
	Average	3.184	3.904	-0.720
	Min	3.071	3.265	-1.410
	Std Dev	0.090	0.373	0.370

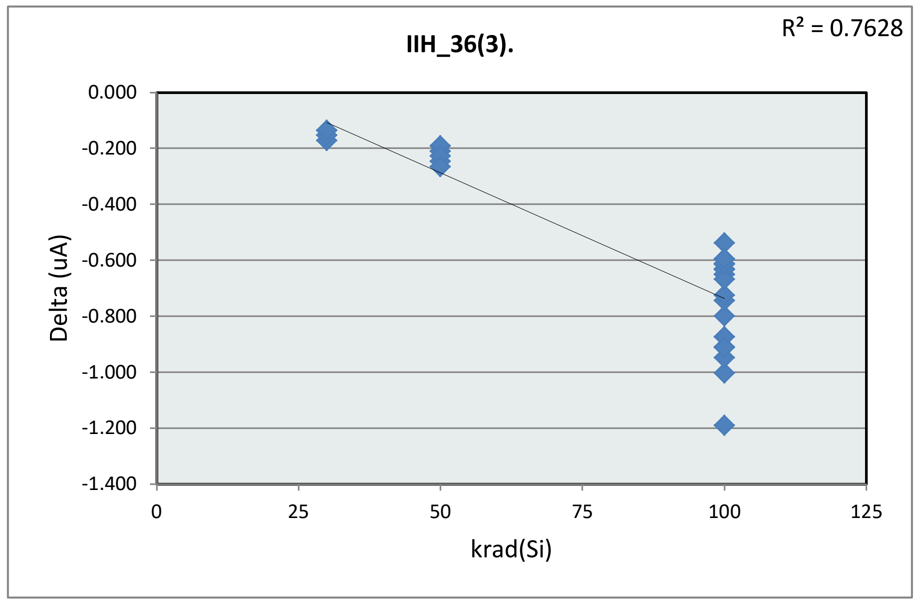


	IIH_36(2).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.265	3.432	3.869
Average	3.332	3.488	4.119
Max	3.470	3.618	4.556
UL	25.000	25.000	25.000

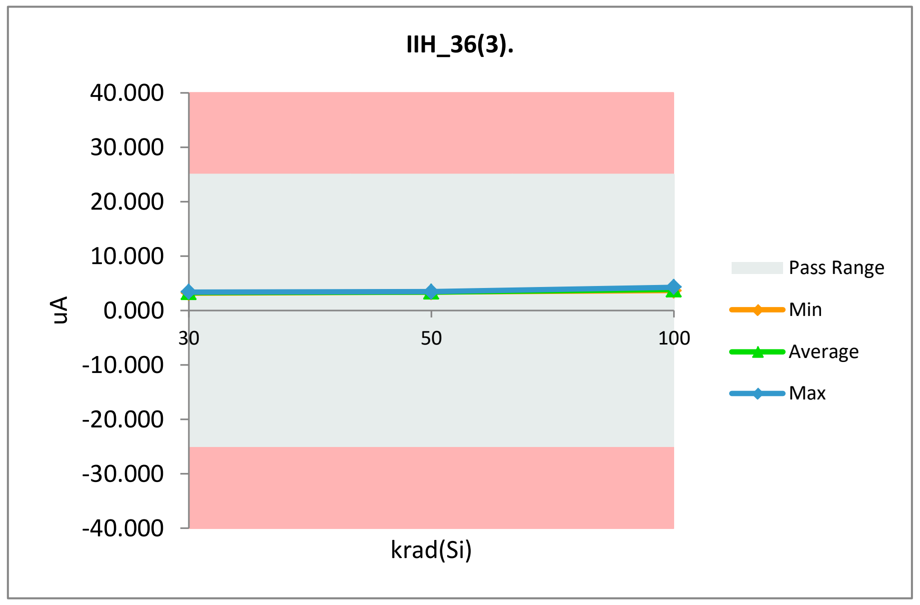


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(3).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	3.181	3.335	-0.154
30	2	3.237	3.409	-0.172
30	3	3.181	3.335	-0.154
30	4	3.107	3.242	-0.135
30	5	3.107	3.242	-0.135
50	11	3.237	3.447	-0.210
50	12	3.181	3.428	-0.247
50	13	3.200	3.391	-0.191
50	14	3.274	3.502	-0.228
50	15	3.144	3.409	-0.265
100	22	3.159	4.033	-0.874
100	23	3.234	4.145	-0.911
100	24	3.215	4.015	-0.800
100	25	3.103	3.847	-0.744
100	26	3.178	3.791	-0.613
100	27	3.085	3.736	-0.651
100	28	3.122	3.773	-0.651
100	29	3.178	3.810	-0.632
100	30	3.047	3.680	-0.633
100	31	3.159	3.773	-0.614
100	32	3.215	3.810	-0.595
100	33	3.271	3.810	-0.539
100	34	3.122	4.313	-1.191
100	35	3.085	4.089	-1.004
100	36	3.122	3.996	-0.874
100	37	3.103	4.052	-0.949
100	38	3.345	4.257	-0.912
100	39	3.122	3.847	-0.725
100	40	3.066	3.698	-0.632
100	41	3.178	3.847	-0.669
100	42	3.085	3.698	-0.613
100	43	3.122	3.717	-0.595
100	44	3.122	3.717	-0.595
	Max	3.345	4.313	-0.135
	Average	3.160	3.733	-0.573
	Min	3.047	3.242	-1.191
	Std Dev	0.068	0.289	0.293

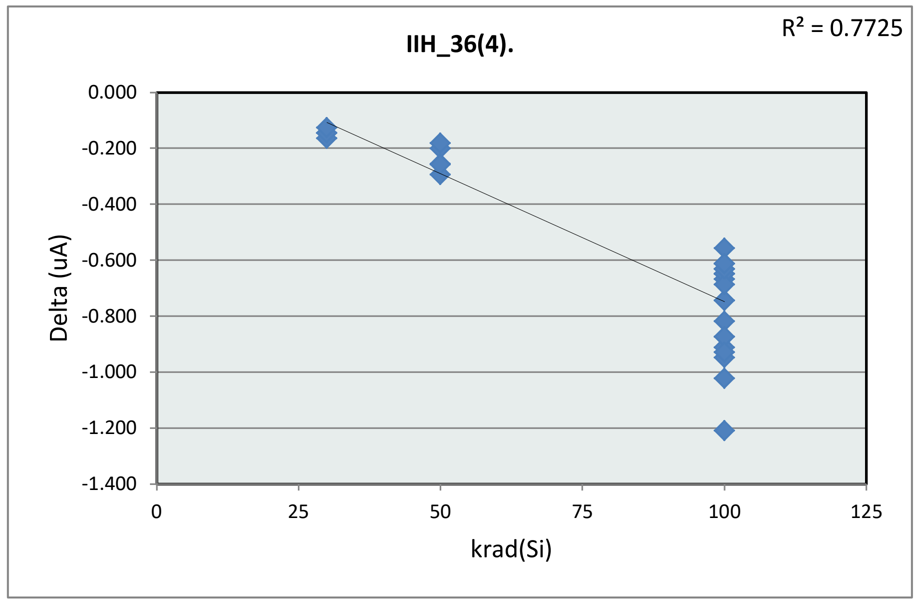


	IIH_36(3).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.242	3.391	3.680
Average	3.313	3.435	3.889
Max	3.409	3.502	4.313
UL	25.000	25.000	25.000

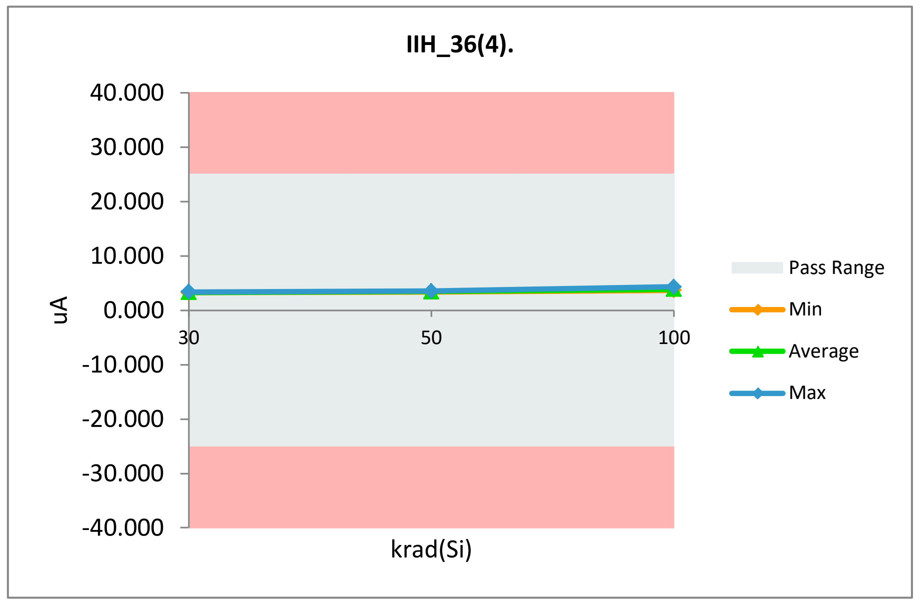


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(4).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	3.185	3.331	-0.146
30	2	3.241	3.387	-0.146
30	3	3.167	3.331	-0.164
30	4	3.111	3.257	-0.146
30	5	3.111	3.238	-0.127
50	11	3.241	3.443	-0.202
50	12	3.167	3.461	-0.294
50	13	3.185	3.368	-0.183
50	14	3.260	3.517	-0.257
50	15	3.148	3.406	-0.258
100	22	3.153	4.027	-0.874
100	23	3.227	4.139	-0.912
100	24	3.209	4.027	-0.818
100	25	3.097	3.841	-0.744
100	26	3.190	3.803	-0.613
100	27	3.097	3.747	-0.650
100	28	3.097	3.766	-0.669
100	29	3.153	3.803	-0.650
100	30	3.041	3.673	-0.632
100	31	3.134	3.766	-0.632
100	32	3.190	3.803	-0.613
100	33	3.283	3.841	-0.558
100	34	3.097	4.306	-1.209
100	35	3.060	4.083	-1.023
100	36	3.134	4.008	-0.874
100	37	3.097	4.045	-0.948
100	38	3.339	4.269	-0.930
100	39	3.097	3.841	-0.744
100	40	3.060	3.710	-0.650
100	41	3.171	3.859	-0.688
100	42	3.078	3.710	-0.632
100	43	3.097	3.710	-0.613
100	44	3.097	3.710	-0.613
	Max	3.339	4.306	-0.127
	Average	3.152	3.734	-0.582
	Min	3.041	3.238	-1.209
	Std Dev	0.070	0.289	0.297

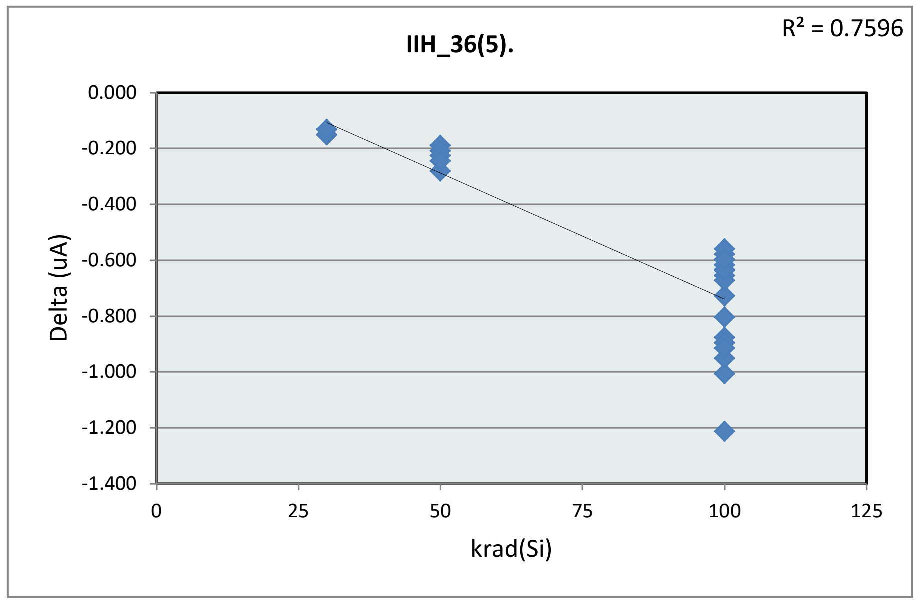


	IIH_36(4).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.238	3.368	3.673
Average	3.309	3.439	3.891
Max	3.387	3.517	4.306
UL	25.000	25.000	25.000

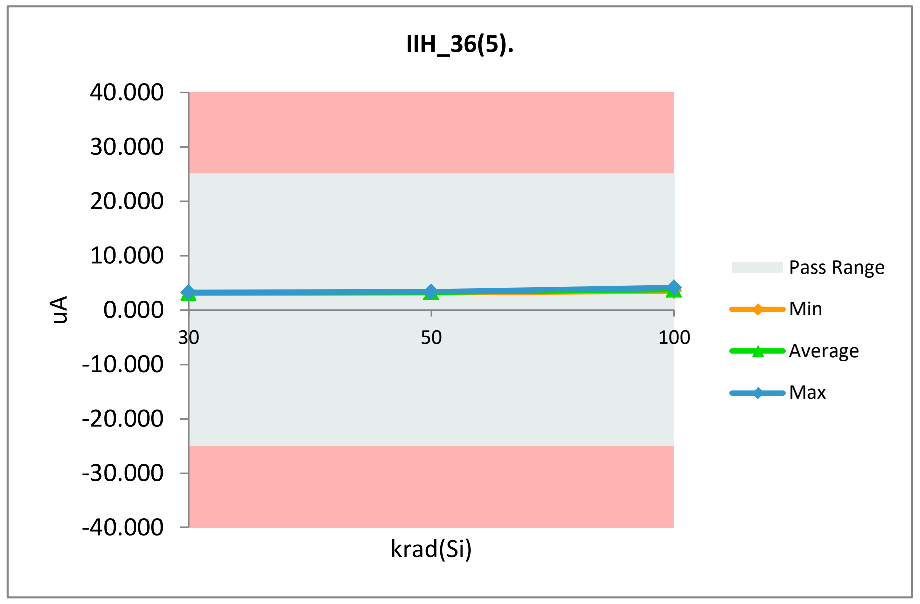


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(5).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	2.994	3.147	-0.153
30	2	3.069	3.221	-0.152
30	3	2.994	3.147	-0.153
30	4	2.920	3.072	-0.152
30	5	2.939	3.072	-0.133
50	11	3.050	3.240	-0.190
50	12	2.976	3.258	-0.282
50	13	2.994	3.203	-0.209
50	14	3.088	3.314	-0.226
50	15	2.976	3.221	-0.245
100	22	2.968	3.846	-0.878
100	23	3.062	3.958	-0.896
100	24	3.024	3.828	-0.804
100	25	2.913	3.641	-0.728
100	26	2.987	3.623	-0.636
100	27	2.913	3.548	-0.635
100	28	2.931	3.567	-0.636
100	29	2.968	3.623	-0.655
100	30	2.875	3.474	-0.599
100	31	2.950	3.586	-0.636
100	32	3.043	3.623	-0.580
100	33	3.099	3.660	-0.561
100	34	2.931	4.144	-1.213
100	35	2.894	3.902	-1.008
100	36	2.931	3.828	-0.897
100	37	2.913	3.865	-0.952
100	38	3.173	4.088	-0.915
100	39	2.931	3.660	-0.729
100	40	2.875	3.492	-0.617
100	41	2.987	3.660	-0.673
100	42	2.894	3.530	-0.636
100	43	2.931	3.530	-0.599
100	44	2.931	3.530	-0.599
	Max	3.173	4.144	-0.133
	Average	2.973	3.549	-0.575
	Min	2.875	3.072	-1.213
	Std Dev	0.071	0.291	0.296



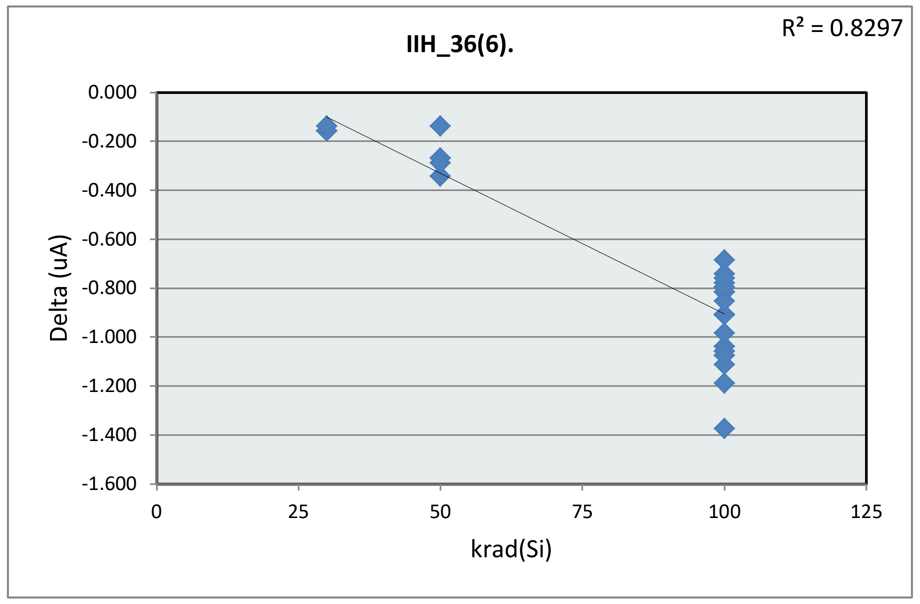
	IIH_36(5).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.072	3.203	3.474
Average	3.132	3.247	3.705
Max	3.221	3.314	4.144
UL	25.000	25.000	25.000



HDR TID Report T0 data
SN55LVCP22A-SP

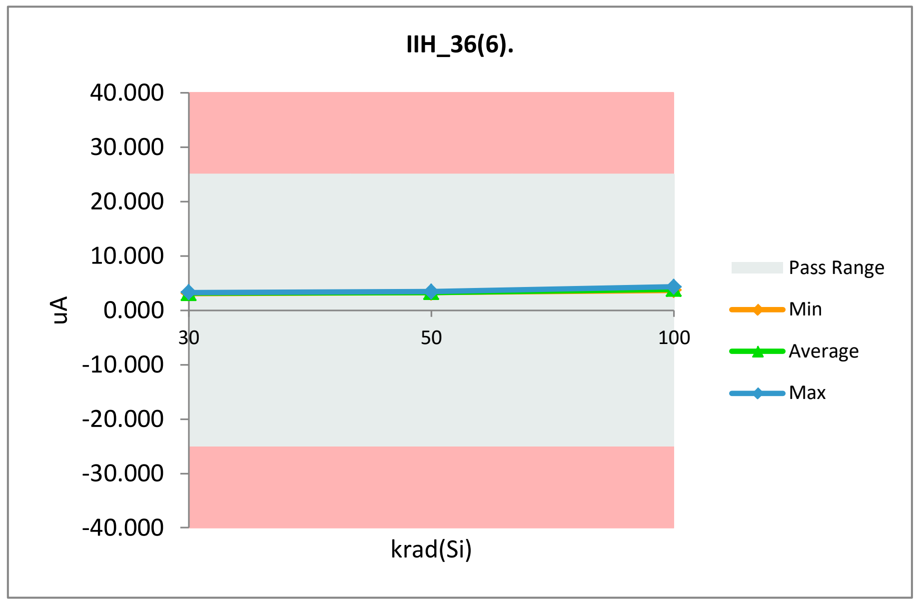
	IIH_36(6).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	2.977	3.116	-0.139
30	2	3.126	3.284	-0.158
30	3	2.959	3.116	-0.157
30	4	2.922	3.079	-0.157
30	5	2.940	3.079	-0.139
50	11	3.089	3.228	-0.139
50	12	2.977	3.321	-0.344
50	13	2.977	3.247	-0.270
50	14	3.145	3.414	-0.269
50	15	2.940	3.228	-0.288
100	22	3.016	4.054	-1.038
100	23	3.109	4.166	-1.057
100	24	3.071	4.054	-0.983
100	25	2.923	3.831	-0.908
100	26	3.016	3.813	-0.797
100	27	2.923	3.738	-0.815
100	28	2.923	3.738	-0.815
100	29	2.978	3.794	-0.816
100	30	2.886	3.664	-0.778
100	31	2.960	3.757	-0.797
100	32	3.090	3.831	-0.741
100	33	3.183	3.869	-0.686
100	34	2.960	4.333	-1.373
100	35	2.904	4.092	-1.188
100	36	2.904	3.961	-1.057
100	37	2.923	4.036	-1.113
100	38	3.220	4.296	-1.076
100	39	2.960	3.869	-0.909
100	40	2.904	3.701	-0.797
100	41	3.016	3.869	-0.853
100	42	2.904	3.701	-0.797
100	43	2.960	3.720	-0.760
100	44	2.960	3.720	-0.760
	Max	3.220	4.333	-0.139
	Average	2.992	3.688	-0.696
	Min	2.886	3.079	-1.373
	Std Dev	0.088	0.363	0.360



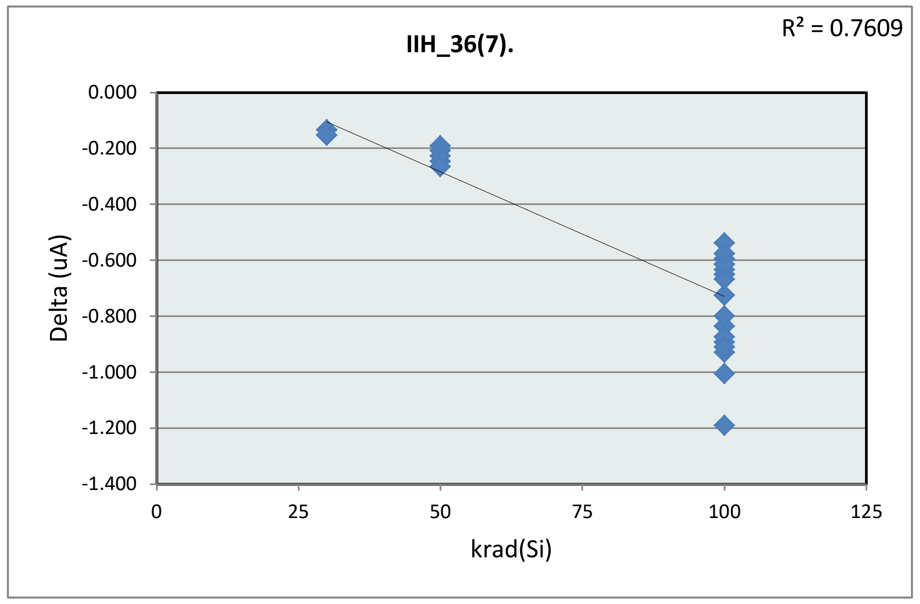
	IIH_36(6).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.079	3.228	3.664
Average	3.135	3.288	3.896
Max	3.284	3.414	4.333
UL	25.000	25.000	25.000

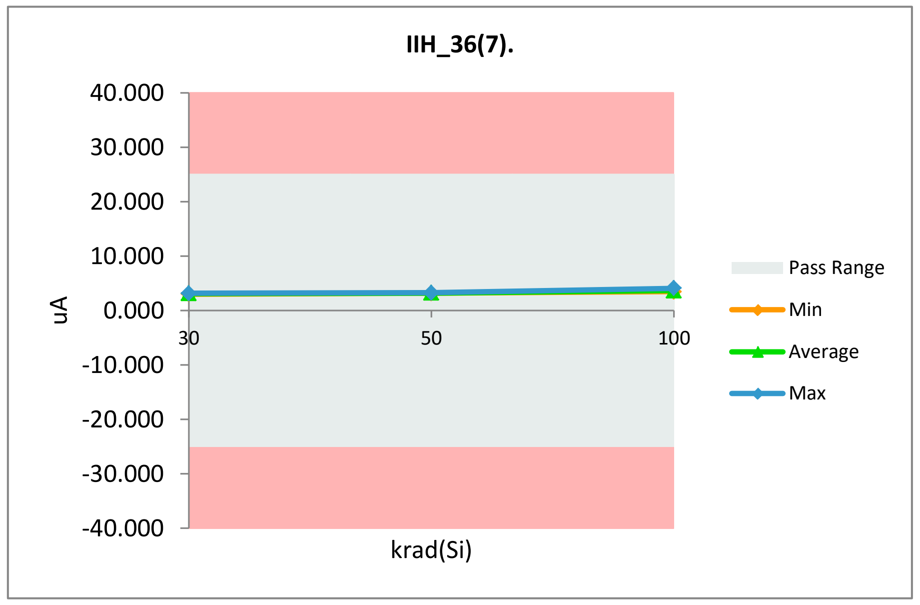


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(7).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	2.995	3.148	-0.153
30	2	3.051	3.204	-0.153
30	3	2.995	3.130	-0.135
30	4	2.920	3.055	-0.135
30	5	2.920	3.074	-0.154
50	11	3.051	3.242	-0.191
50	12	2.995	3.242	-0.247
50	13	2.995	3.204	-0.209
50	14	3.069	3.298	-0.229
50	15	2.958	3.223	-0.265
100	22	2.992	3.829	-0.837
100	23	3.047	3.940	-0.893
100	24	3.029	3.829	-0.800
100	25	2.917	3.642	-0.725
100	26	2.992	3.587	-0.595
100	27	2.898	3.549	-0.651
100	28	2.936	3.587	-0.651
100	29	2.973	3.624	-0.651
100	30	2.880	3.475	-0.595
100	31	2.954	3.587	-0.633
100	32	3.029	3.624	-0.595
100	33	3.085	3.624	-0.539
100	34	2.936	4.127	-1.191
100	35	2.898	3.903	-1.005
100	36	2.936	3.810	-0.874
100	37	2.936	3.866	-0.930
100	38	3.141	4.052	-0.911
100	39	2.936	3.661	-0.725
100	40	2.898	3.512	-0.614
100	41	2.992	3.661	-0.669
100	42	2.898	3.512	-0.614
100	43	2.936	3.512	-0.576
100	44	2.936	3.512	-0.576
	Max	3.141	4.127	-0.135
	Average	2.973	3.541	-0.567
	Min	2.880	3.055	-1.191
	Std Dev	0.063	0.288	0.291

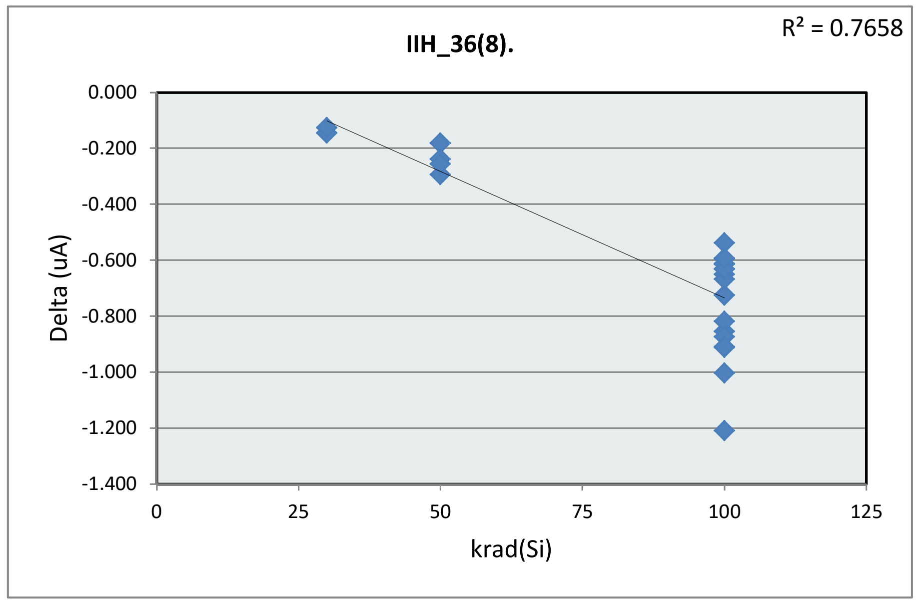


	IIH_36(7).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.055	3.204	3.475
Average	3.122	3.242	3.697
Max	3.204	3.298	4.127
UL	25.000	25.000	25.000

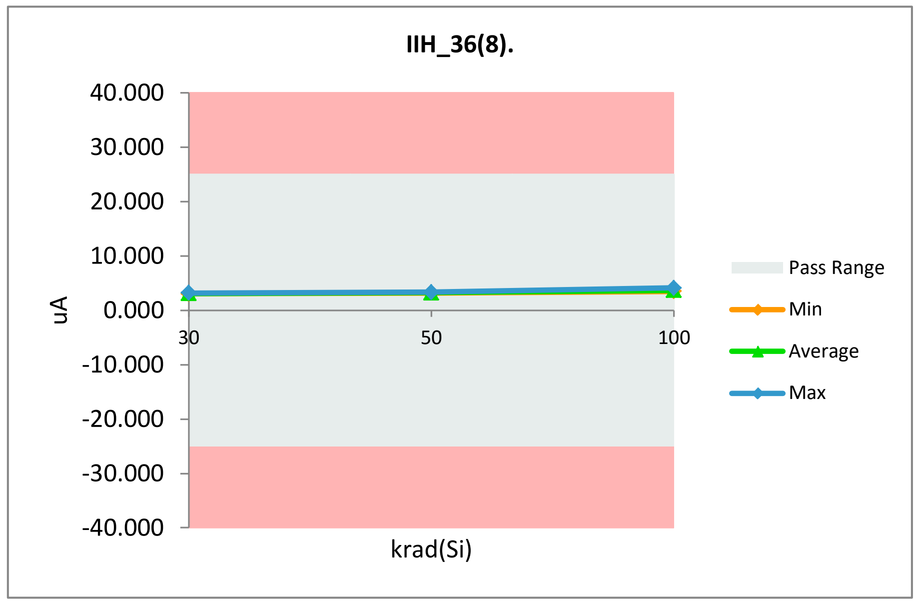


HDR TID Report T0 data
SN55LVCP22A-SP

		IIH_36(8).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	2.999	3.126	-0.127
30	2	3.055	3.201	-0.146
30	3	2.981	3.126	-0.145
30	4	2.925	3.070	-0.145
30	5	2.925	3.052	-0.127
50	11	3.055	3.238	-0.183
50	12	2.981	3.275	-0.294
50	13	2.999	3.182	-0.183
50	14	3.074	3.312	-0.238
50	15	2.962	3.219	-0.257
100	22	2.985	3.841	-0.856
100	23	3.041	3.952	-0.911
100	24	3.022	3.841	-0.819
100	25	2.911	3.636	-0.725
100	26	2.985	3.599	-0.614
100	27	2.911	3.543	-0.632
100	28	2.929	3.580	-0.651
100	29	2.967	3.599	-0.632
100	30	2.873	3.468	-0.595
100	31	2.948	3.580	-0.632
100	32	3.004	3.617	-0.613
100	33	3.097	3.636	-0.539
100	34	2.911	4.120	-1.209
100	35	2.892	3.896	-1.004
100	36	2.929	3.803	-0.874
100	37	2.929	3.841	-0.912
100	38	3.153	4.064	-0.911
100	39	2.929	3.654	-0.725
100	40	2.873	3.505	-0.632
100	41	2.985	3.654	-0.669
100	42	2.873	3.505	-0.632
100	43	2.911	3.505	-0.594
100	44	2.911	3.505	-0.594
	Max	3.153	4.120	-0.127
	Average	2.967	3.538	-0.570
	Min	2.873	3.052	-1.209
	Std Dev	0.068	0.289	0.295



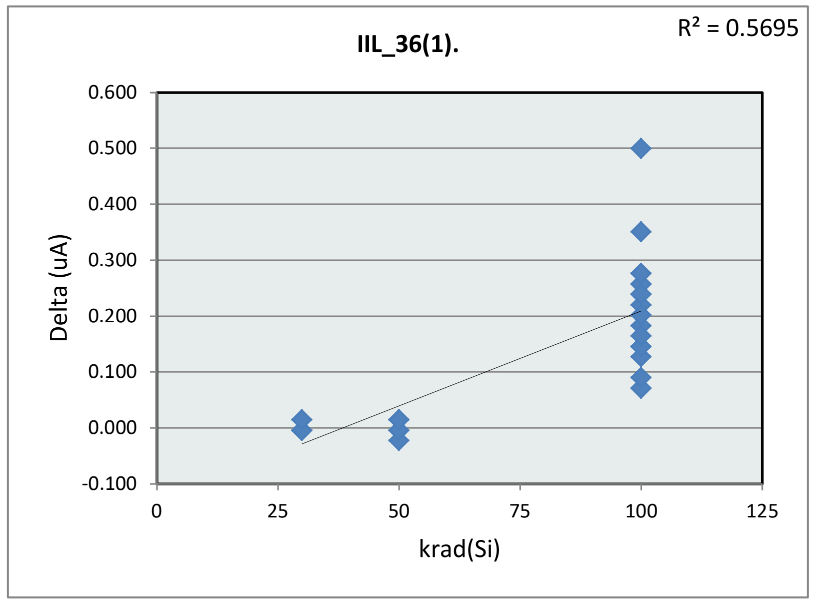
	IIH_36(8).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	uA	
Min Limit	-25	uA	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	3.052	3.182	3.468
Average	3.115	3.245	3.693
Max	3.201	3.312	4.120
UL	25.000	25.000	25.000



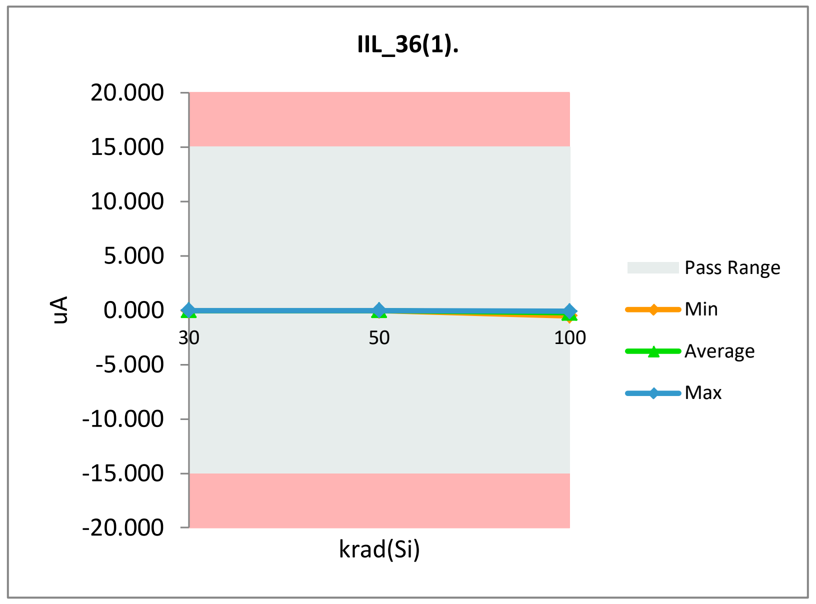
HDR TID Report T0 data
SN55LVCP22A-SP

	IIL_36(1).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-0.023	-0.019	-0.004
30	2	-0.023	-0.019	-0.004
30	3	-0.023	-0.019	-0.004
30	4	-0.023	-0.019	-0.004
30	5	-0.023	-0.037	0.014
50	11	-0.023	-0.019	-0.004
50	12	-0.042	-0.019	-0.023
50	13	-0.023	-0.019	-0.004
50	14	-0.023	-0.037	0.014
50	15	-0.023	-0.037	0.014
100	22	-0.031	-0.102	0.071
100	23	-0.049	-0.120	0.071
100	24	-0.012	-0.157	0.145
100	25	-0.012	-0.511	0.499
100	26	-0.031	-0.381	0.350
100	27	-0.031	-0.288	0.257
100	28	-0.031	-0.269	0.238
100	29	-0.012	-0.139	0.127
100	30	-0.031	-0.250	0.220
100	31	-0.031	-0.176	0.145
100	32	-0.049	-0.306	0.257
100	33	-0.031	-0.213	0.182
100	34	-0.031	-0.102	0.071
100	35	-0.031	-0.232	0.201
100	36	-0.031	-0.269	0.238
100	37	-0.031	-0.195	0.164
100	38	-0.031	-0.120	0.089
100	39	-0.031	-0.288	0.257
100	40	-0.012	-0.288	0.276
100	41	-0.012	-0.269	0.257
100	42	-0.031	-0.306	0.276
100	43	-0.031	-0.269	0.238
100	44	-0.031	-0.269	0.238
	Max	-0.012	-0.019	0.499
	Average	-0.027	-0.175	0.147
	Min	-0.049	-0.511	-0.023
	Std Dev	0.009	0.129	0.129

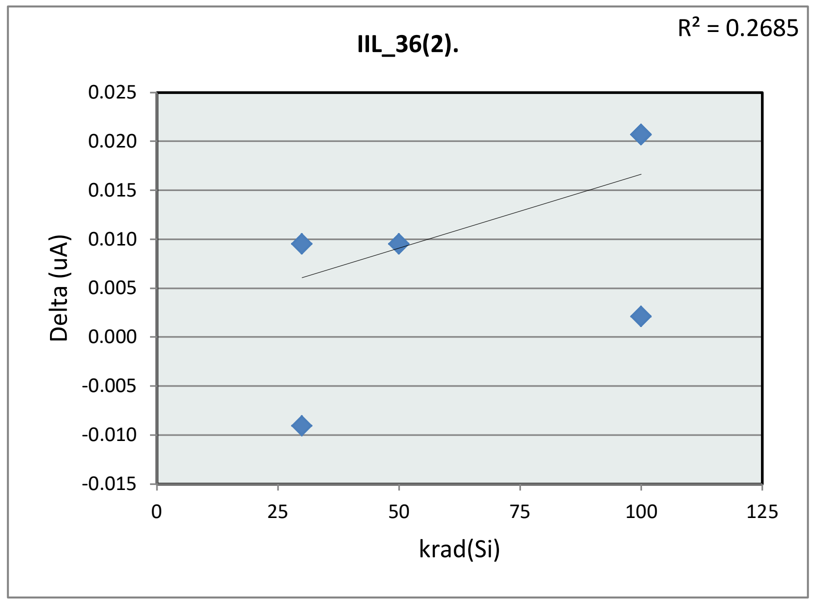


	IIL_36(1).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.037	-0.037	-0.511
Average	-0.022	-0.026	-0.240
Max	-0.019	-0.019	-0.102
UL	15.000	15.000	15.000

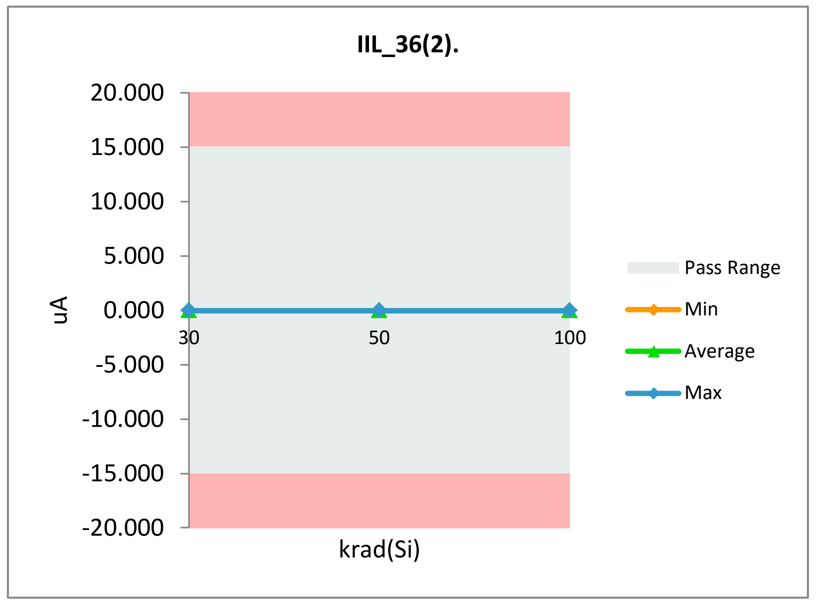


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	-0.016	-0.025	0.009
30	2	-0.016	-0.025	0.009
30	3	-0.016	-0.025	0.009
30	4	-0.034	-0.025	-0.009
30	5	-0.016	-0.025	0.009
50	11	-0.016	-0.025	0.009
50	12	-0.016	-0.025	0.009
50	13	-0.016	-0.025	0.009
50	14	-0.016	-0.025	0.009
50	15	-0.016	-0.025	0.009
100	22	-0.014	-0.034	0.021
100	23	-0.014	-0.034	0.021
100	24	-0.014	-0.034	0.021
100	25	-0.014	-0.016	0.002
100	26	-0.014	-0.034	0.021
100	27	-0.014	-0.034	0.021
100	28	-0.014	-0.034	0.021
100	29	-0.032	-0.034	0.002
100	30	-0.014	-0.016	0.002
100	31	-0.014	-0.016	0.002
100	32	-0.014	-0.034	0.021
100	33	-0.014	-0.034	0.021
100	34	-0.014	-0.034	0.021
100	35	-0.014	-0.034	0.021
100	36	-0.014	-0.034	0.021
100	37	-0.014	-0.034	0.021
100	38	-0.014	-0.034	0.021
100	39	-0.014	-0.034	0.021
100	40	-0.014	-0.034	0.021
100	41	-0.014	-0.034	0.021
100	42	-0.014	-0.016	0.002
100	43	-0.014	-0.034	0.021
100	44	-0.014	-0.034	0.021
	Max	-0.014	-0.016	0.021
	Average	-0.015	-0.029	0.014
	Min	-0.034	-0.034	-0.009
	Std Dev	0.005	0.007	0.008

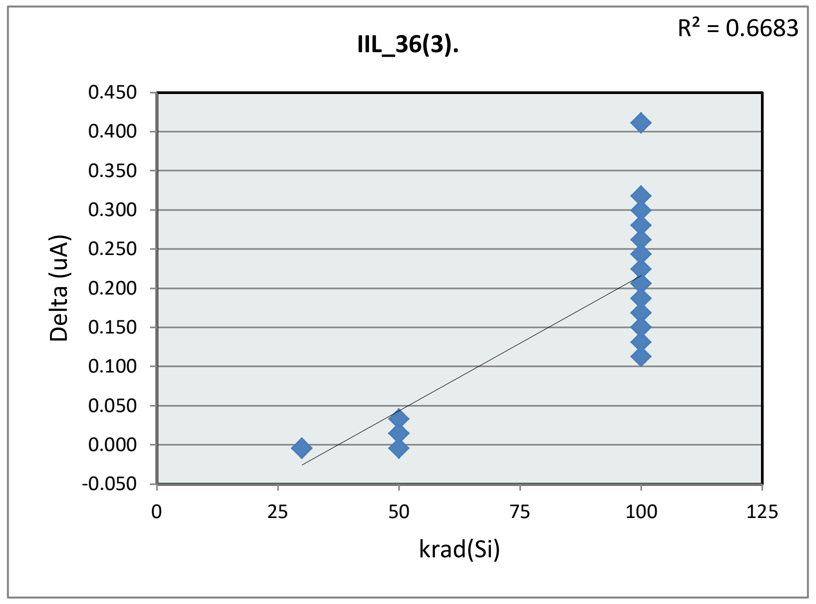


	IIL_36(2).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.025	-0.025	-0.034
Average	-0.025	-0.025	-0.031
Max	-0.025	-0.025	-0.016
UL	15.000	15.000	15.000

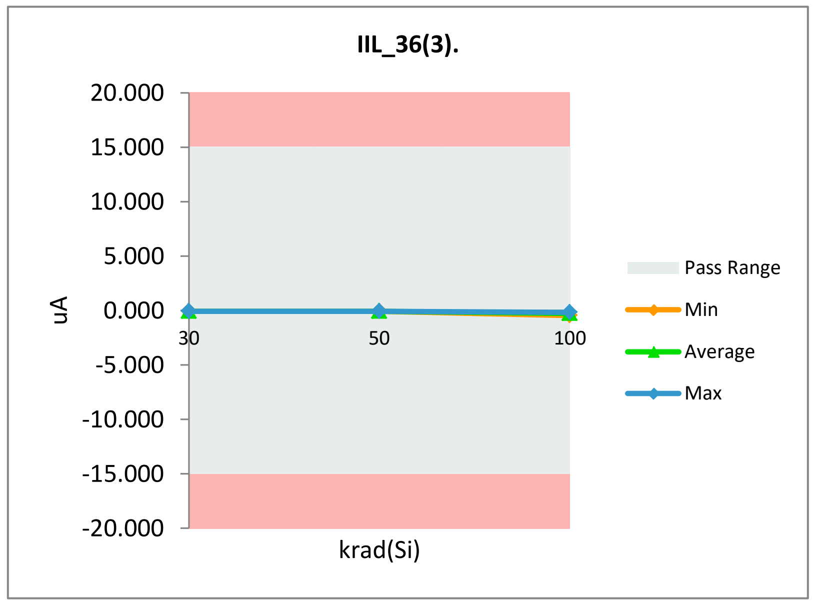


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(3).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.041	-0.037	-0.004
30	2	-0.041	-0.037	-0.004
30	3	-0.041	-0.037	-0.004
30	4	-0.041	-0.037	-0.004
30	5	-0.041	-0.037	-0.004
50	11	-0.041	-0.055	0.014
50	12	-0.041	-0.037	-0.004
50	13	-0.023	-0.037	0.014
50	14	-0.023	-0.055	0.033
50	15	-0.023	-0.037	0.014
100	22	-0.025	-0.138	0.113
100	23	-0.025	-0.250	0.224
100	24	-0.025	-0.231	0.206
100	25	-0.025	-0.231	0.206
100	26	-0.025	-0.343	0.318
100	27	-0.025	-0.436	0.411
100	28	-0.025	-0.194	0.169
100	29	-0.025	-0.175	0.150
100	30	-0.025	-0.212	0.187
100	31	-0.025	-0.306	0.280
100	32	-0.044	-0.306	0.262
100	33	-0.025	-0.194	0.169
100	34	-0.025	-0.157	0.131
100	35	-0.025	-0.231	0.206
100	36	-0.025	-0.324	0.299
100	37	-0.025	-0.175	0.150
100	38	-0.025	-0.212	0.187
100	39	-0.044	-0.194	0.150
100	40	-0.025	-0.268	0.243
100	41	-0.025	-0.268	0.243
100	42	-0.025	-0.436	0.411
100	43	-0.025	-0.175	0.150
100	44	-0.025	-0.175	0.150
	Max	-0.023	-0.037	0.411
	Average	-0.029	-0.183	0.153
	Min	-0.044	-0.436	-0.004
	Std Dev	0.008	0.117	0.120

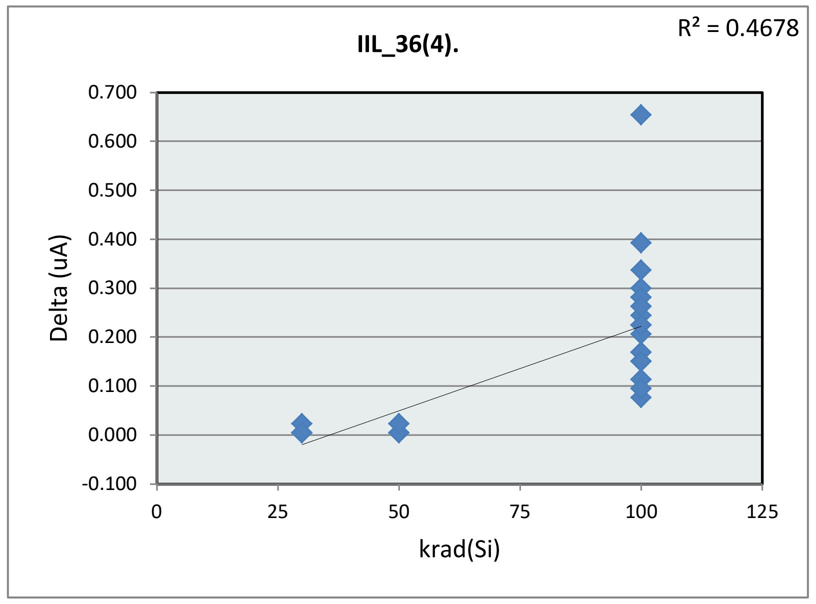


	IIL_36(3).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.037	-0.055	-0.436
Average	-0.037	-0.044	-0.245
Max	-0.037	-0.037	-0.138
UL	15.000	15.000	15.000

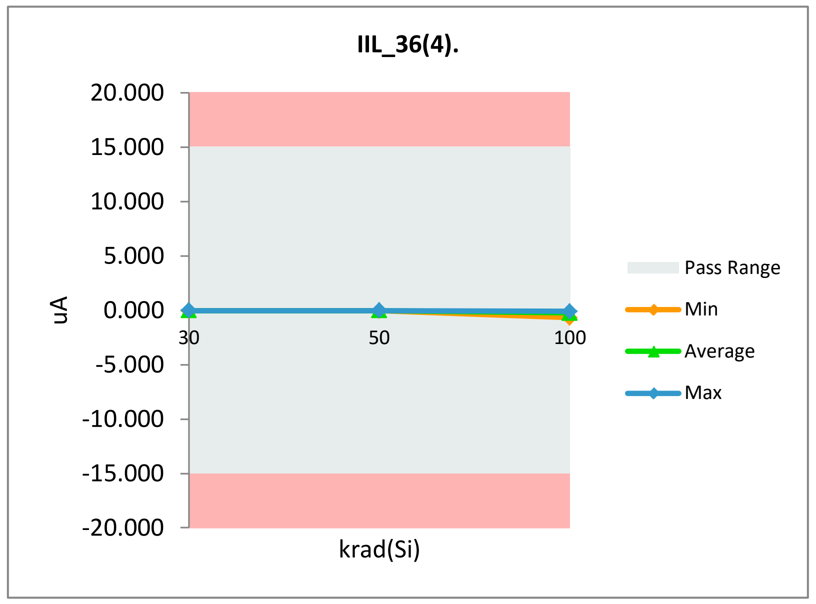


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(4).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-0.017	-0.021	0.004
30	2	-0.017	-0.040	0.023
30	3	-0.017	-0.021	0.004
30	4	-0.017	-0.021	0.004
30	5	-0.017	-0.021	0.004
50	11	-0.036	-0.040	0.004
50	12	-0.017	-0.021	0.004
50	13	-0.017	-0.040	0.023
50	14	-0.017	-0.021	0.004
50	15	-0.017	-0.040	0.023
100	22	-0.013	-0.126	0.113
100	23	-0.013	-0.349	0.337
100	24	-0.031	-0.144	0.113
100	25	-0.013	-0.238	0.225
100	26	-0.013	-0.163	0.150
100	27	-0.013	-0.275	0.262
100	28	-0.013	-0.312	0.299
100	29	-0.013	-0.163	0.150
100	30	-0.013	-0.182	0.169
100	31	-0.013	-0.405	0.393
100	32	-0.013	-0.219	0.206
100	33	-0.013	-0.238	0.225
100	34	-0.013	-0.089	0.076
100	35	-0.013	-0.182	0.169
100	36	-0.013	-0.293	0.281
100	37	-0.031	-0.312	0.281
100	38	-0.013	-0.256	0.244
100	39	-0.031	-0.685	0.653
100	40	-0.013	-0.163	0.150
100	41	-0.013	-0.238	0.225
100	42	-0.013	-0.275	0.262
100	43	-0.013	-0.107	0.095
100	44	-0.013	-0.107	0.095
	Max	-0.013	-0.021	0.653
	Average	-0.016	-0.176	0.160
	Min	-0.036	-0.685	0.004
	Std Dev	0.006	0.145	0.144

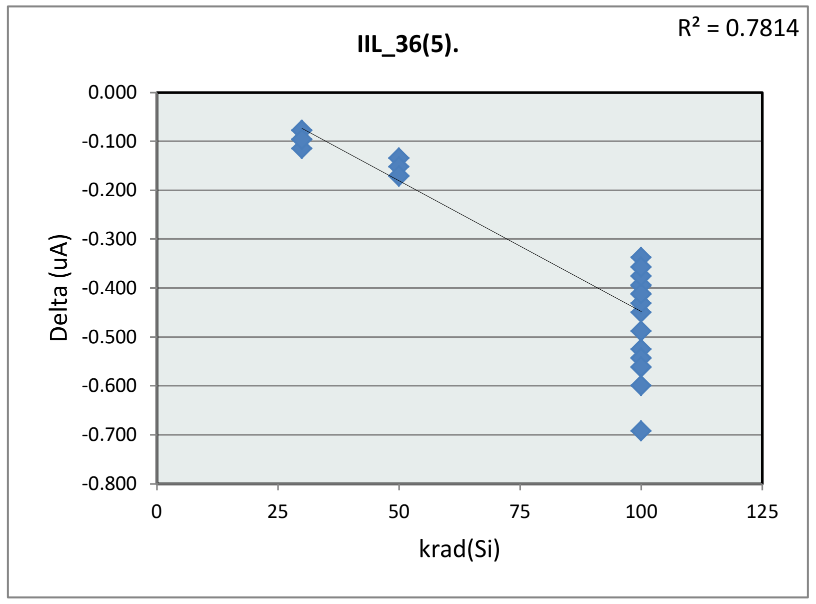


	IIL_36(4).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.040	-0.040	-0.685
Average	-0.025	-0.033	-0.240
Max	-0.021	-0.021	-0.089
UL	15.000	15.000	15.000

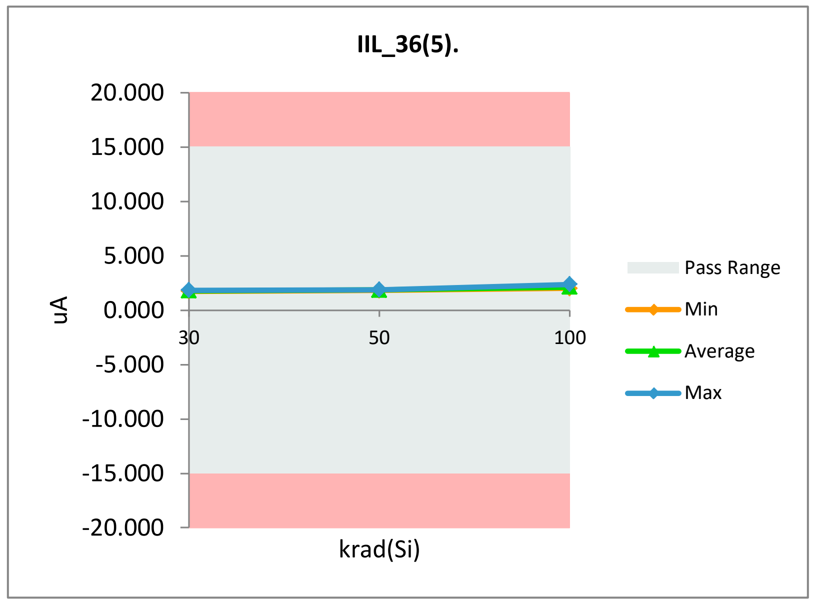


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(5).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.709	1.787	-0.078
30	2	1.728	1.843	-0.115
30	3	1.691	1.787	-0.096
30	4	1.672	1.750	-0.078
30	5	1.672	1.769	-0.097
50	11	1.728	1.862	-0.134
50	12	1.691	1.862	-0.171
50	13	1.691	1.825	-0.134
50	14	1.746	1.899	-0.153
50	15	1.672	1.843	-0.171
100	22	1.683	2.208	-0.525
100	23	1.739	2.282	-0.543
100	24	1.720	2.208	-0.488
100	25	1.646	2.096	-0.450
100	26	1.683	2.077	-0.394
100	27	1.646	2.040	-0.394
100	28	1.664	2.059	-0.395
100	29	1.683	2.096	-0.413
100	30	1.627	2.003	-0.376
100	31	1.683	2.059	-0.376
100	32	1.720	2.077	-0.357
100	33	1.758	2.096	-0.338
100	34	1.683	2.375	-0.692
100	35	1.646	2.245	-0.599
100	36	1.664	2.208	-0.544
100	37	1.646	2.208	-0.562
100	38	1.795	2.356	-0.561
100	39	1.664	2.096	-0.432
100	40	1.646	2.040	-0.394
100	41	1.702	2.114	-0.412
100	42	1.664	2.040	-0.376
100	43	1.664	2.021	-0.357
100	44	1.664	2.021	-0.357
	Max	1.795	2.375	-0.078
	Average	1.688	2.038	-0.350
	Min	1.627	1.750	-0.692
	Std Dev	0.038	0.172	0.173

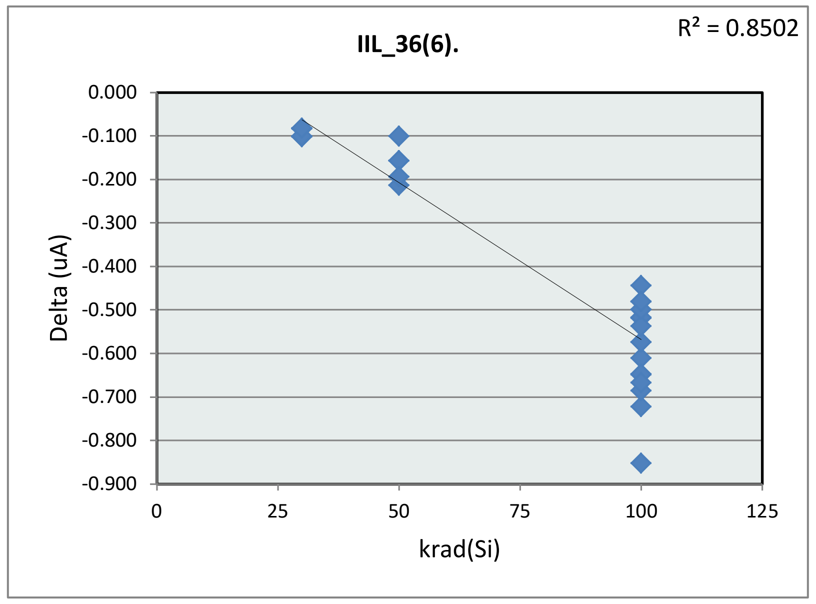


	IIL_36(5).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	1.750	1.825	2.003
Average	1.787	1.858	2.132
Max	1.843	1.899	2.375
UL	15.000	15.000	15.000

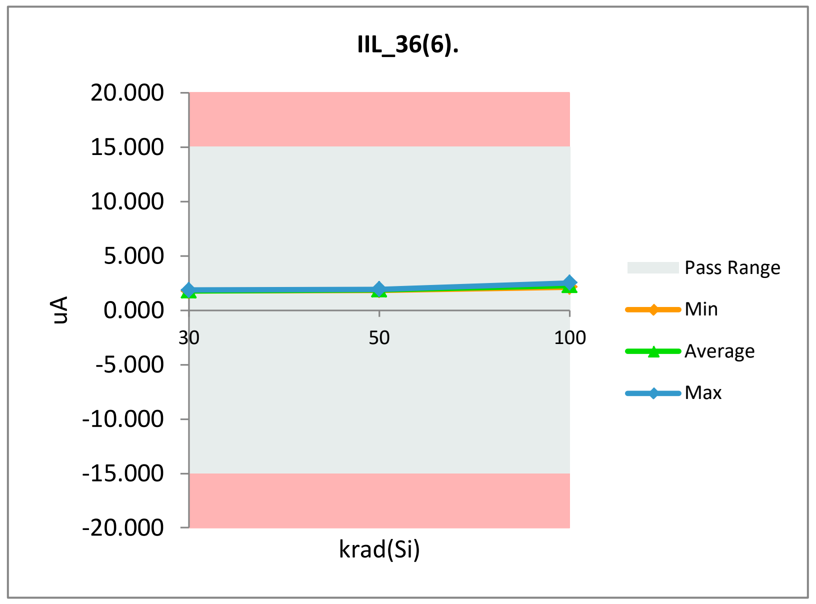


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(6).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.695	1.778	-0.083
30	2	1.769	1.871	-0.102
30	3	1.676	1.778	-0.102
30	4	1.657	1.759	-0.102
30	5	1.676	1.759	-0.083
50	11	1.750	1.852	-0.102
50	12	1.695	1.908	-0.213
50	13	1.695	1.852	-0.157
50	14	1.788	1.945	-0.157
50	15	1.657	1.852	-0.195
100	22	1.715	2.363	-0.648
100	23	1.770	2.419	-0.649
100	24	1.752	2.363	-0.611
100	25	1.659	2.233	-0.574
100	26	1.715	2.215	-0.500
100	27	1.659	2.177	-0.518
100	28	1.659	2.177	-0.518
100	29	1.696	2.215	-0.519
100	30	1.640	2.140	-0.500
100	31	1.696	2.196	-0.500
100	32	1.752	2.233	-0.481
100	33	1.808	2.252	-0.444
100	34	1.678	2.530	-0.852
100	35	1.659	2.382	-0.723
100	36	1.659	2.307	-0.648
100	37	1.659	2.345	-0.686
100	38	1.826	2.493	-0.667
100	39	1.678	2.252	-0.574
100	40	1.659	2.177	-0.518
100	41	1.715	2.252	-0.537
100	42	1.659	2.159	-0.500
100	43	1.678	2.159	-0.481
100	44	1.678	2.159	-0.481
	Max	1.826	2.530	-0.083
	Average	1.701	2.138	-0.437
	Min	1.640	1.759	-0.852
	Std Dev	0.049	0.225	0.223

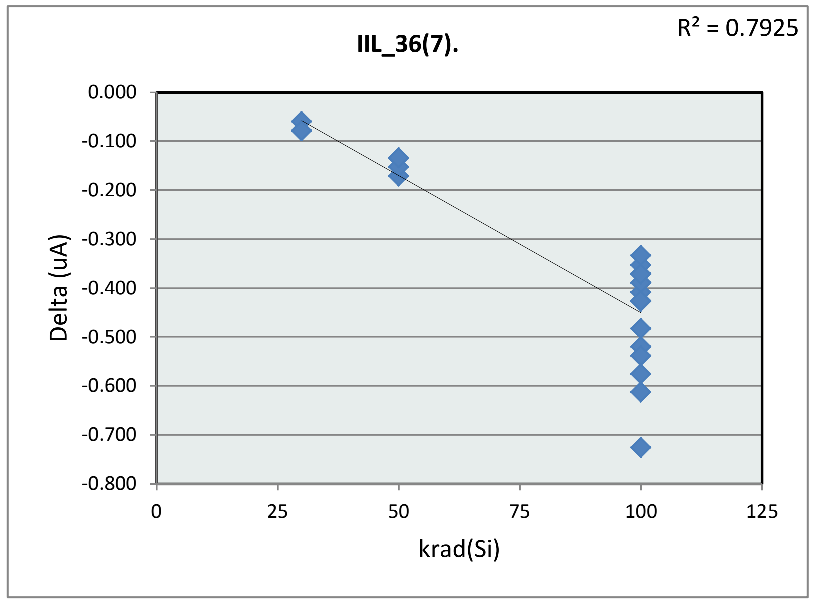


	IIL_36(6).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	1.759	1.852	2.140
Average	1.789	1.882	2.269
Max	1.871	1.945	2.530
UL	15.000	15.000	15.000

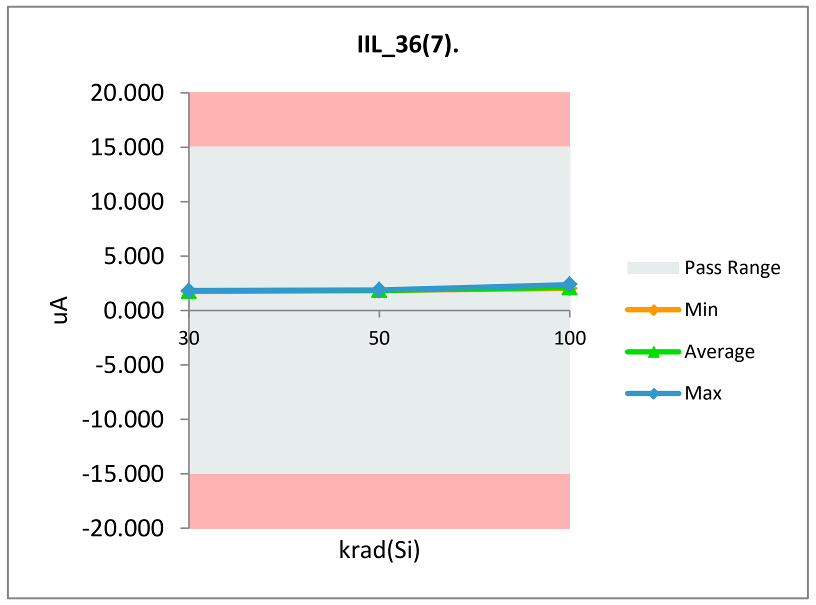


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(7).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.710	1.789	-0.079
30	2	1.747	1.826	-0.079
30	3	1.710	1.789	-0.079
30	4	1.672	1.733	-0.061
30	5	1.672	1.751	-0.079
50	11	1.728	1.863	-0.135
50	12	1.691	1.863	-0.172
50	13	1.710	1.845	-0.135
50	14	1.747	1.900	-0.153
50	15	1.691	1.826	-0.135
100	22	1.707	2.227	-0.520
100	23	1.744	2.283	-0.539
100	24	1.725	2.208	-0.483
100	25	1.669	2.097	-0.428
100	26	1.707	2.078	-0.371
100	27	1.651	2.041	-0.390
100	28	1.651	2.078	-0.427
100	29	1.707	2.097	-0.390
100	30	1.632	2.022	-0.390
100	31	1.688	2.078	-0.390
100	32	1.725	2.078	-0.353
100	33	1.763	2.097	-0.334
100	34	1.669	2.395	-0.726
100	35	1.651	2.264	-0.613
100	36	1.688	2.208	-0.520
100	37	1.651	2.227	-0.576
100	38	1.800	2.339	-0.539
100	39	1.688	2.115	-0.427
100	40	1.632	2.041	-0.409
100	41	1.688	2.115	-0.427
100	42	1.651	2.041	-0.390
100	43	1.669	2.041	-0.372
100	44	1.669	2.041	-0.372
	Max	1.800	2.395	-0.061
	Average	1.694	2.042	-0.348
	Min	1.632	1.733	-0.726
	Std Dev	0.039	0.176	0.180

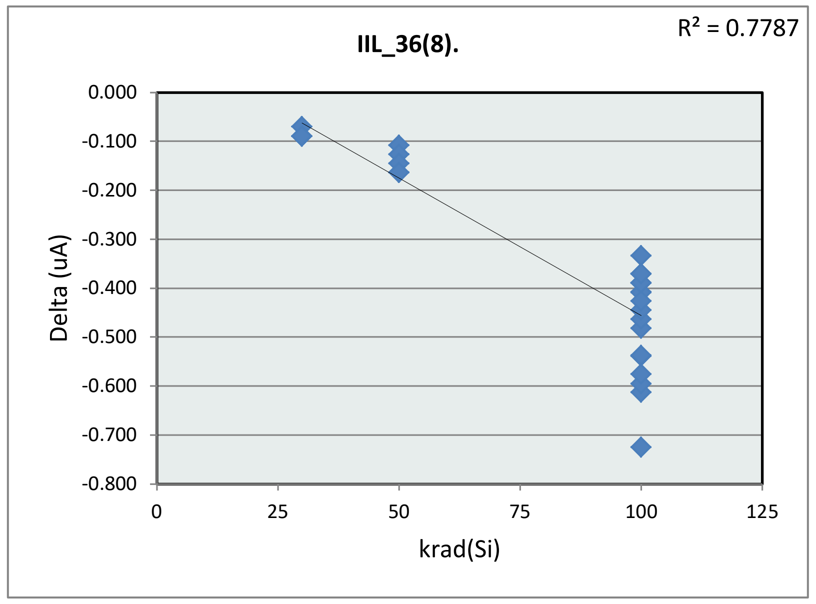


	IIL_36(7).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	1.733	1.826	2.022
Average	1.778	1.859	2.140
Max	1.826	1.900	2.395
UL	15.000	15.000	15.000

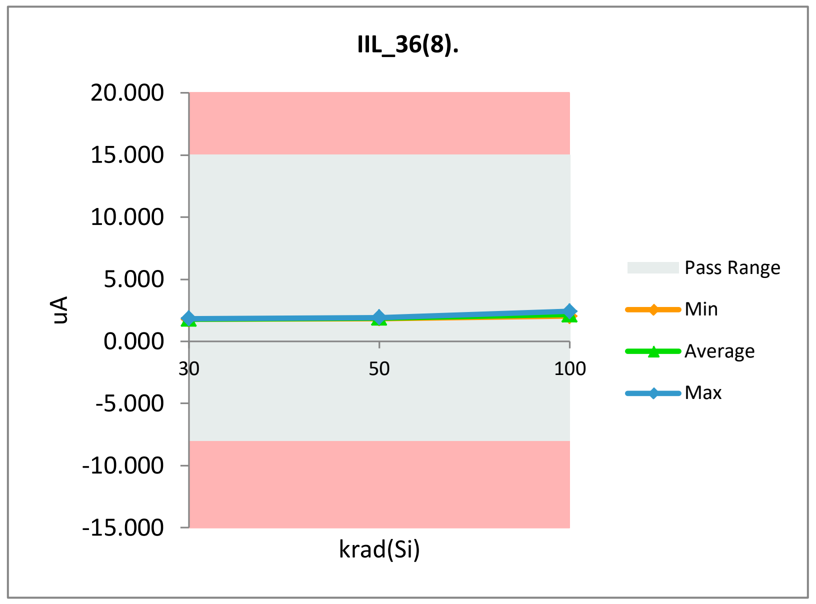


HDR TID Report T0 data
SN55LVCP22A-SP

		IIL_36(8).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-8	-8	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	1.714	1.785	-0.071
30	2	1.752	1.841	-0.089
30	3	1.714	1.804	-0.090
30	4	1.677	1.767	-0.090
30	5	1.677	1.767	-0.090
50	11	1.752	1.860	-0.108
50	12	1.714	1.878	-0.164
50	13	1.714	1.841	-0.127
50	14	1.770	1.916	-0.146
50	15	1.696	1.860	-0.164
100	22	1.700	2.239	-0.539
100	23	1.756	2.295	-0.539
100	24	1.738	2.220	-0.482
100	25	1.663	2.127	-0.464
100	26	1.719	2.090	-0.371
100	27	1.682	2.072	-0.390
100	28	1.682	2.090	-0.408
100	29	1.700	2.109	-0.409
100	30	1.645	2.034	-0.389
100	31	1.700	2.090	-0.390
100	32	1.738	2.109	-0.371
100	33	1.775	2.109	-0.334
100	34	1.682	2.407	-0.725
100	35	1.663	2.276	-0.613
100	36	1.682	2.220	-0.538
100	37	1.663	2.258	-0.595
100	38	1.793	2.369	-0.576
100	39	1.682	2.127	-0.445
100	40	1.663	2.053	-0.390
100	41	1.719	2.146	-0.427
100	42	1.663	2.053	-0.390
100	43	1.682	2.053	-0.371
100	44	1.682	2.053	-0.371
	Max	1.793	2.407	-0.071
	Average	1.705	2.058	-0.354
	Min	1.645	1.767	-0.725
	Std Dev	0.037	0.178	0.182

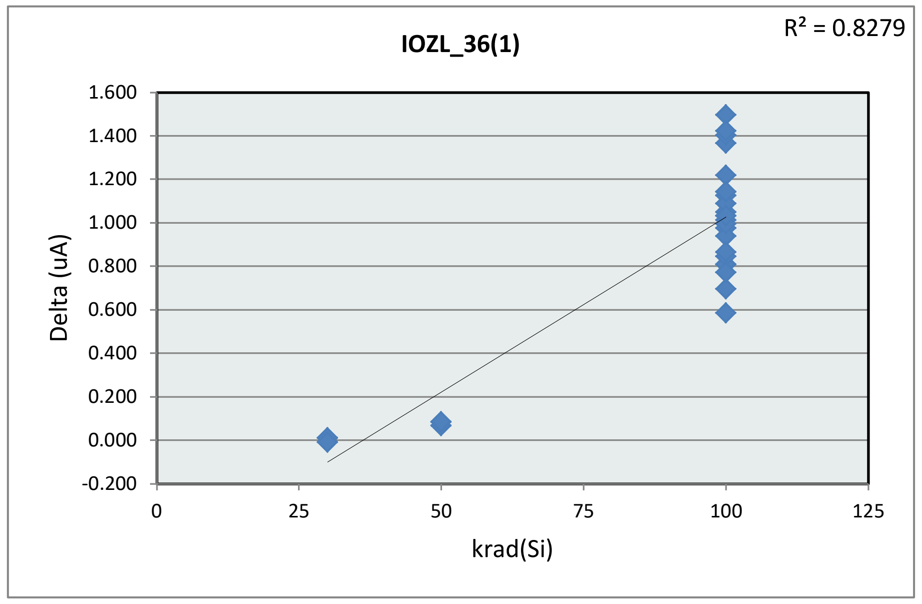


	IIL_36(8).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-8	uA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	1.767	1.841	2.034
Average	1.793	1.871	2.156
Max	1.841	1.916	2.407
UL	15.000	15.000	15.000

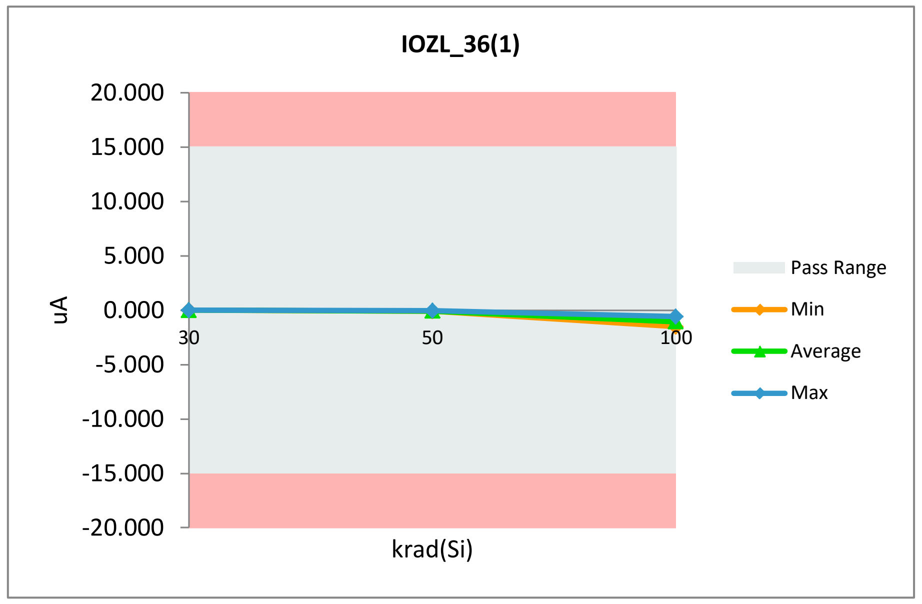


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.022	0.011	0.011
30	2	0.003	-0.007	0.011
30	3	-0.015	-0.007	-0.008
30	4	0.003	-0.007	0.011
30	5	0.003	0.011	-0.008
50	11	-0.015	-0.100	0.085
50	12	-0.015	-0.082	0.066
50	13	-0.015	-0.100	0.085
50	14	0.022	-0.044	0.066
50	15	0.003	-0.082	0.085
100	22	-0.028	-1.152	1.124
100	23	-0.028	-0.836	0.808
100	24	-0.010	-0.985	0.976
100	25	-0.010	-1.376	1.366
100	26	-0.010	-0.818	0.808
100	27	-0.028	-0.966	0.938
100	28	-0.028	-0.874	0.845
100	29	-0.028	-0.725	0.697
100	30	-0.028	-1.041	1.013
100	31	-0.010	-1.059	1.049
100	32	-0.010	-0.874	0.864
100	33	-0.028	-0.799	0.771
100	34	-0.028	-1.431	1.403
100	35	-0.010	-1.097	1.087
100	36	-0.028	-1.171	1.143
100	37	-0.028	-1.022	0.994
100	38	-0.010	-0.595	0.585
100	39	-0.028	-1.524	1.496
100	40	-0.010	-1.227	1.217
100	41	-0.010	-1.431	1.421
100	42	-0.028	-1.171	1.143
100	43	-0.028	-1.059	1.031
100	44	-0.028	-1.059	1.031
	Max	0.022	0.011	1.496
	Average	-0.015	-0.748	0.734
	Min	-0.028	-1.524	-0.008
	Std Dev	0.015	0.514	0.505

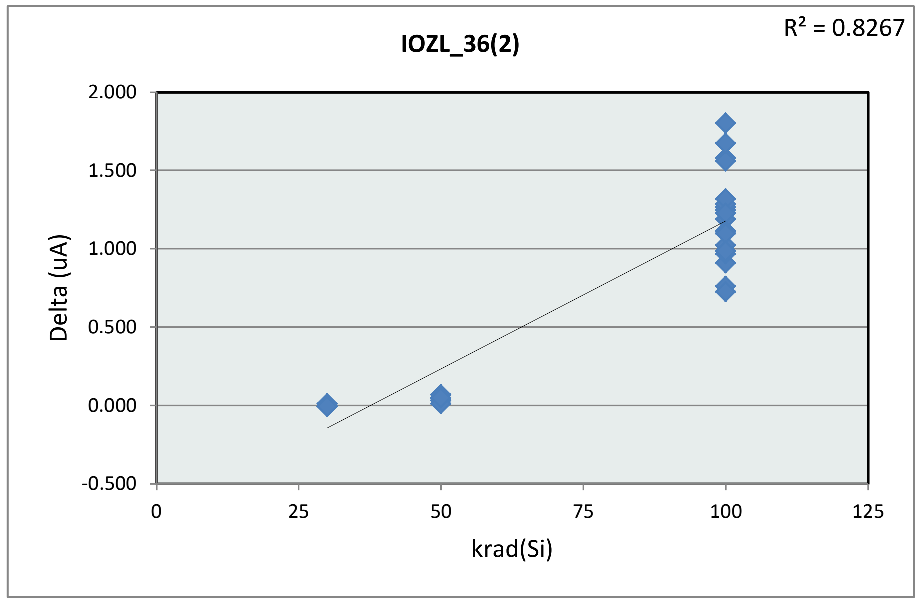


	IOZL_36(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.007	-0.100	-1.524
Average	0.000	-0.082	-1.056
Max	0.011	-0.044	-0.595
UL	15.000	15.000	15.000

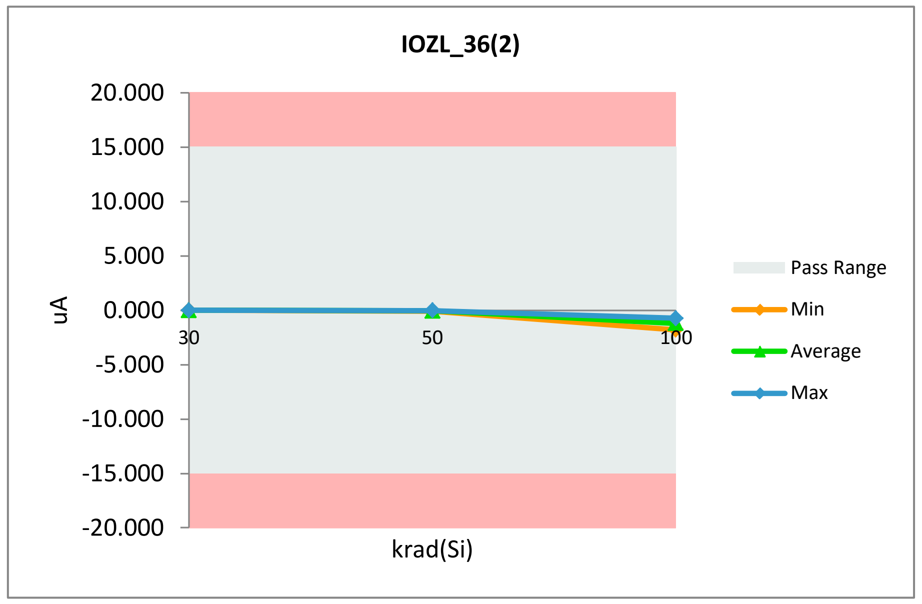


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.005	0.003	-0.008
30	2	-0.005	0.003	-0.008
30	3	-0.005	0.003	-0.008
30	4	0.013	0.003	0.011
30	5	-0.005	0.003	-0.008
50	11	-0.005	-0.072	0.066
50	12	-0.005	-0.035	0.029
50	13	-0.005	-0.053	0.048
50	14	-0.005	-0.016	0.011
50	15	-0.005	-0.053	0.048
100	22	-0.010	-1.292	1.282
100	23	-0.010	-1.273	1.263
100	24	-0.010	-1.255	1.245
100	25	0.008	-1.571	1.579
100	26	-0.010	-1.199	1.189
100	27	-0.010	-0.920	0.909
100	28	-0.010	-0.976	0.965
100	29	0.008	-0.752	0.761
100	30	0.008	-0.976	0.984
100	31	0.008	-1.255	1.263
100	32	-0.010	-1.292	1.282
100	33	-0.010	-1.124	1.114
100	34	-0.010	-1.329	1.319
100	35	0.008	-1.217	1.225
100	36	-0.010	-1.031	1.021
100	37	-0.010	-1.124	1.114
100	38	-0.010	-0.734	0.723
100	39	-0.010	-1.571	1.561
100	40	-0.010	-1.683	1.673
100	41	0.008	-1.794	1.802
100	42	0.008	-1.087	1.095
100	43	-0.010	-0.994	0.984
100	44	-0.010	-0.994	0.984
	Max	0.013	0.003	1.802
	Average	-0.004	-0.838	0.834
	Min	-0.010	-1.794	-0.008
	Std Dev	0.008	0.592	0.592

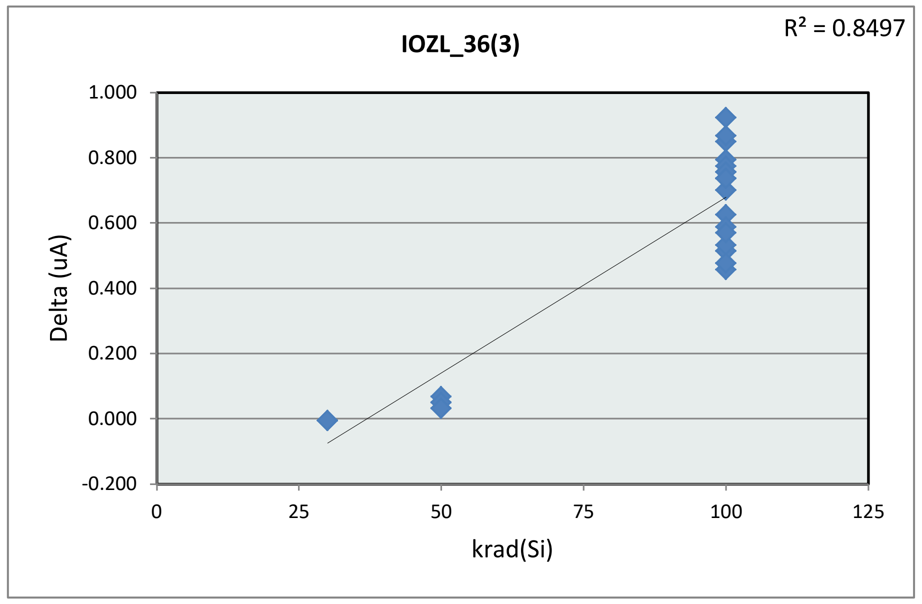


	IOZL_36(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.003	-0.072	-1.794
Average	0.003	-0.046	-1.193
Max	0.003	-0.016	-0.734
UL	15.000	15.000	15.000

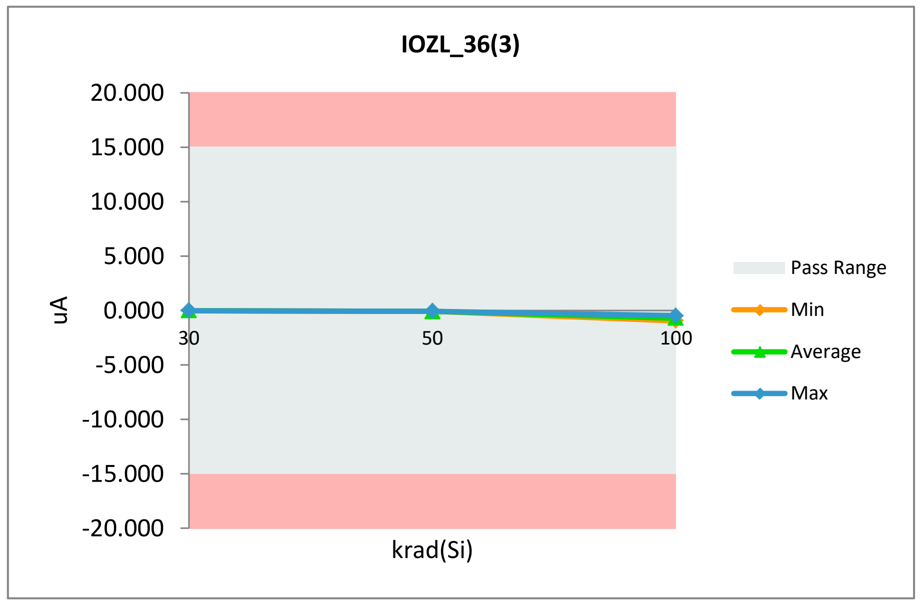


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.016	-0.010	-0.006
30	2	-0.016	-0.010	-0.006
30	3	-0.016	-0.010	-0.006
30	4	-0.016	-0.010	-0.006
30	5	-0.016	-0.010	-0.006
50	11	-0.016	-0.084	0.068
50	12	-0.016	-0.066	0.050
50	13	-0.016	-0.066	0.050
50	14	-0.016	-0.047	0.031
50	15	-0.016	-0.047	0.031
100	22	-0.002	-0.925	0.923
100	23	-0.002	-0.925	0.923
100	24	-0.002	-0.515	0.513
100	25	-0.002	-0.850	0.848
100	26	-0.002	-0.478	0.476
100	27	-0.002	-0.627	0.625
100	28	-0.002	-0.459	0.457
100	29	-0.002	-0.757	0.755
100	30	-0.002	-0.757	0.755
100	31	-0.002	-0.701	0.699
100	32	-0.002	-0.515	0.513
100	33	-0.002	-0.478	0.476
100	34	-0.002	-0.590	0.588
100	35	-0.002	-0.869	0.867
100	36	-0.002	-0.794	0.793
100	37	-0.002	-0.534	0.532
100	38	-0.002	-0.701	0.699
100	39	-0.002	-0.776	0.774
100	40	-0.002	-0.757	0.755
100	41	-0.002	-0.571	0.569
100	42	-0.002	-0.739	0.737
100	43	-0.002	-0.739	0.737
100	44	-0.002	-0.739	0.737
	Max	-0.002	-0.010	0.923
	Average	-0.006	-0.490	0.483
	Min	-0.016	-0.925	-0.006
	Std Dev	0.007	0.327	0.333

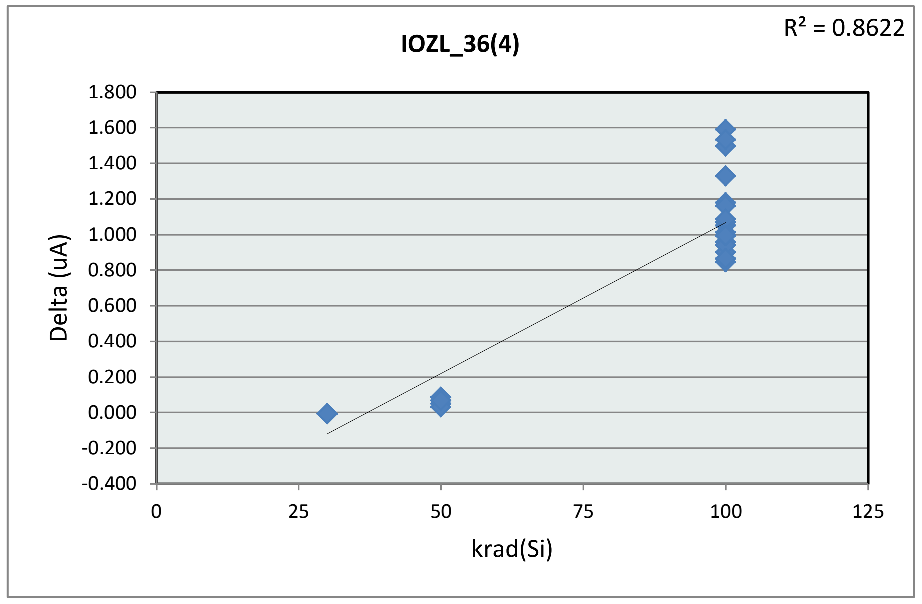


	IOZL_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.010	-0.084	-0.925
Average	-0.010	-0.062	-0.687
Max	-0.010	-0.047	-0.459
UL	15.000	15.000	15.000

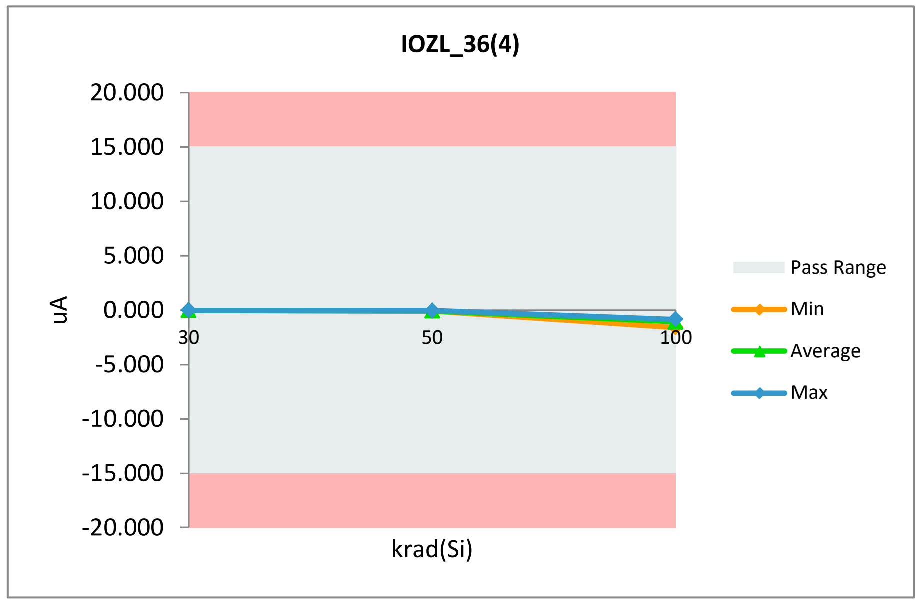


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.019	-0.012	-0.007
30	2	-0.019	-0.012	-0.007
30	3	-0.019	-0.012	-0.007
30	4	-0.019	-0.012	-0.007
30	5	-0.019	-0.012	-0.007
50	11	-0.019	-0.105	0.086
50	12	-0.019	-0.068	0.049
50	13	-0.019	-0.105	0.086
50	14	-0.019	-0.049	0.030
50	15	-0.019	-0.086	0.067
100	22	-0.007	-1.595	1.588
100	23	-0.007	-1.186	1.179
100	24	-0.026	-1.075	1.049
100	25	-0.026	-1.354	1.328
100	26	-0.026	-0.926	0.900
100	27	-0.007	-0.963	0.956
100	28	-0.026	-0.963	0.937
100	29	-0.007	-0.945	0.937
100	30	-0.026	-0.963	0.937
100	31	-0.026	-1.521	1.495
100	32	-0.007	-1.019	1.012
100	33	-0.007	-0.870	0.863
100	34	-0.007	-1.000	0.993
100	35	-0.007	-1.000	0.993
100	36	-0.007	-1.075	1.068
100	37	-0.026	-1.093	1.067
100	38	-0.007	-0.852	0.844
100	39	-0.007	-1.540	1.533
100	40	-0.007	-0.870	0.863
100	41	-0.007	-1.168	1.161
100	42	-0.007	-1.093	1.086
100	43	-0.007	-1.000	0.993
100	44	-0.007	-1.000	0.993
	Max	-0.007	-0.012	1.588
	Average	-0.015	-0.774	0.759
	Min	-0.026	-1.595	-0.007
	Std Dev	0.008	0.519	0.521

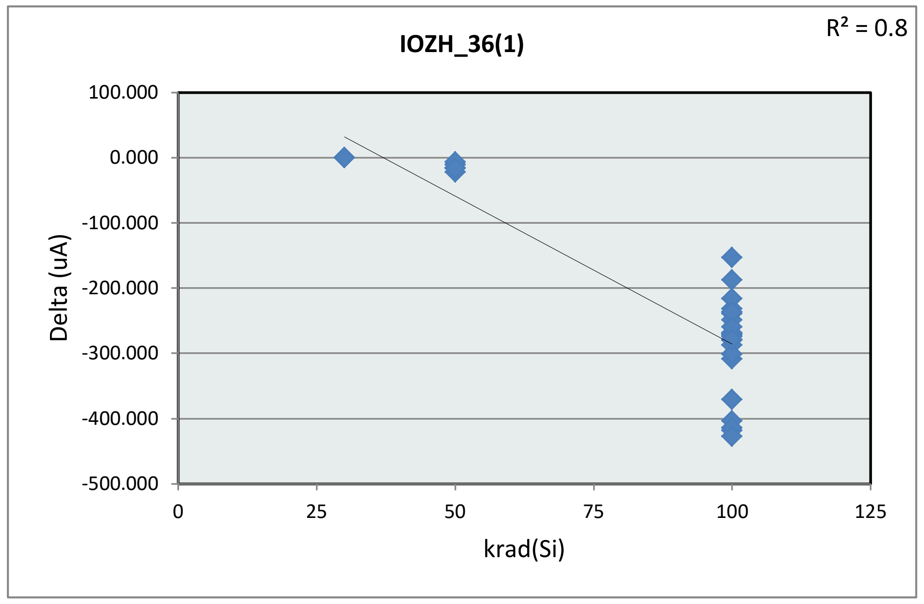


	IOZL_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.012	-0.105	-1.595
Average	-0.012	-0.083	-1.090
Max	-0.012	-0.049	-0.852
UL	15.000	15.000	15.000

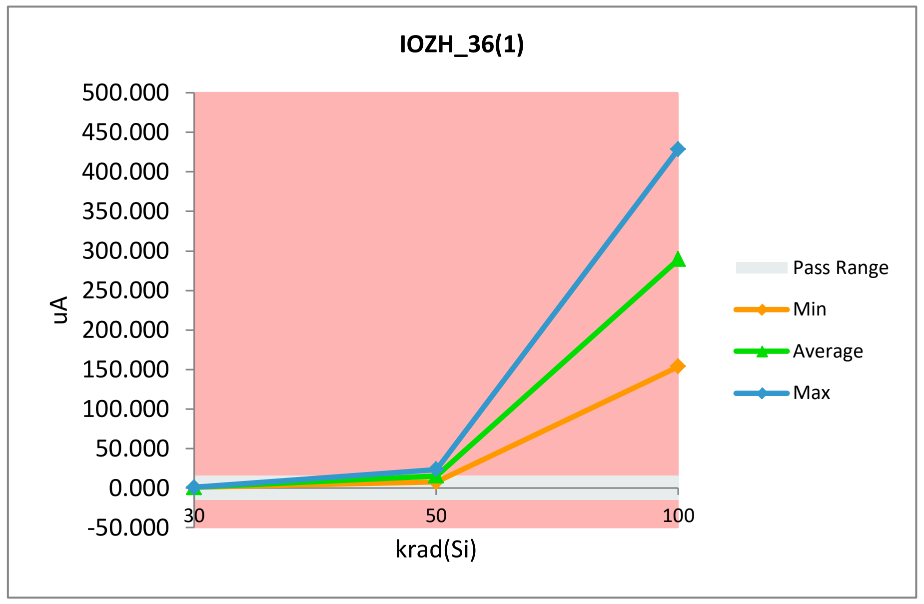


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZH_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	1.008	0.979	0.029
30	2	0.971	0.979	-0.008
30	3	1.026	1.072	-0.046
30	4	1.008	1.016	-0.008
30	5	1.008	0.997	0.010
50	11	0.952	23.649	-22.697
50	12	0.989	12.231	-11.242
50	13	1.045	16.438	-15.393
50	14	0.915	7.724	-6.809
50	15	1.008	17.640	-16.632
100	22	1.146	249.989	-248.843
100	23	1.146	271.591	-270.445
100	24	0.845	269.191	-268.346
100	25	1.146	404.804	-403.658
100	26	1.146	233.188	-232.042
100	27	1.146	240.389	-239.243
100	28	1.146	217.587	-216.441
100	29	1.146	188.784	-187.638
100	30	1.146	272.792	-271.646
100	31	1.146	281.192	-280.046
100	32	1.146	275.192	-274.046
100	33	1.146	237.989	-236.843
100	34	1.146	372.401	-371.255
100	35	1.146	288.393	-287.247
100	36	1.146	309.995	-308.849
100	37	1.146	260.790	-259.644
100	38	1.146	153.981	-152.835
100	39	1.146	419.206	-418.060
100	40	1.146	415.605	-414.459
100	41	1.146	428.806	-427.660
100	42	1.446	302.794	-301.348
100	43	1.146	279.992	-278.846
100	44	1.146	279.992	-278.846
	Max	1.446	428.806	0.029
	Average	1.100	204.163	-203.063
	Min	0.845	0.979	-427.660
	Std Dev	0.106	144.688	144.621

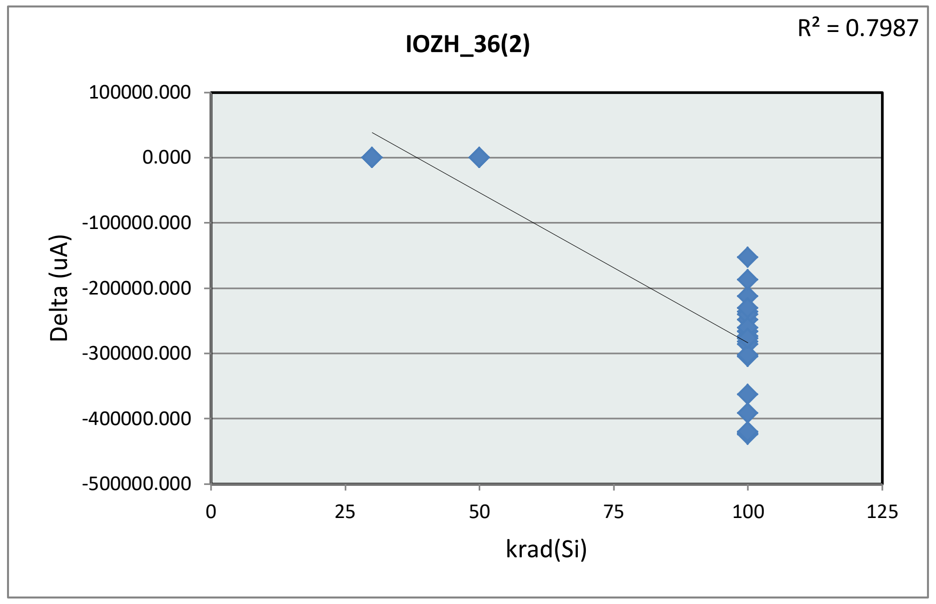


	IOZH_36(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.979	7.724	153.981
Average	1.009	15.536	289.332
Max	1.072	23.649	428.806
UL	15.000	15.000	15.000

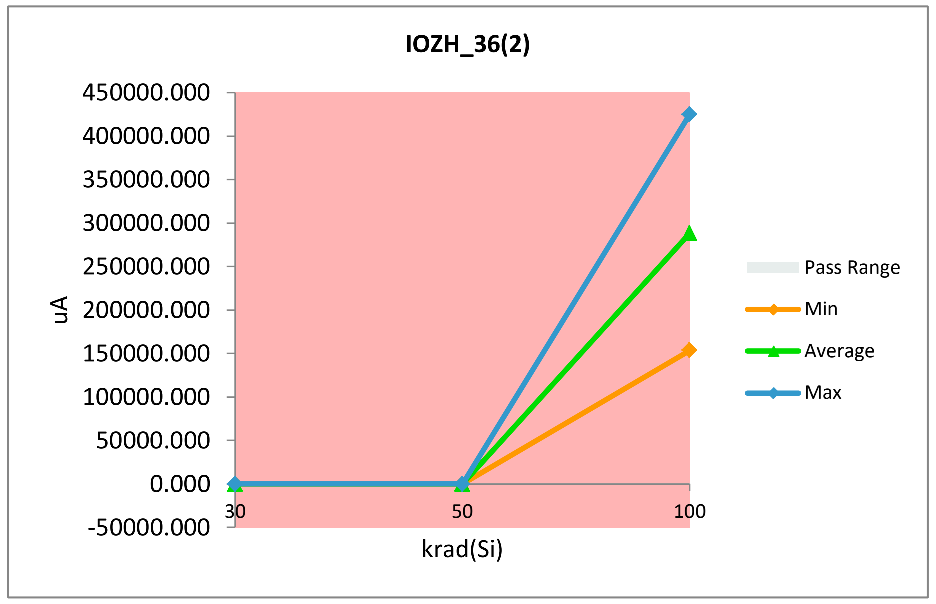


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.000	0.989	0.011
30	2	0.962	0.952	0.011
30	3	1.037	1.045	-0.008
30	4	1.000	1.026	-0.026
30	5	1.018	0.989	0.029
50	11	0.944	23.481	-22.537
50	12	1.000	12.057	-11.057
50	13	1.037	15.664	-14.627
50	14	0.925	7.848	-6.923
50	15	1.018	17.168	-16.150
100	22	1135.000	249748.000	-248613.000
100	23	834.747	274967.000	-274132.253
100	24	1135.000	267762.000	-266627.000
100	25	1135.000	392659.000	-391524.000
100	26	1135.000	237739.000	-236604.000
100	27	1135.000	241341.000	-240206.000
100	28	1135.000	213720.000	-212585.000
100	29	1135.000	188500.000	-187365.000
100	30	1135.000	267762.000	-266627.000
100	31	1135.000	283374.000	-282239.000
100	32	1135.000	274967.000	-273832.000
100	33	1135.000	231734.000	-230599.000
100	34	1135.000	363837.000	-362702.000
100	35	1135.000	286977.000	-285842.000
100	36	1135.000	306191.000	-305056.000
100	37	1135.000	261757.000	-260622.000
100	38	1135.000	153673.000	-152538.000
100	39	1135.000	423883.000	-422748.000
100	40	1135.000	425084.000	-423949.000
100	41	1135.000	421481.000	-420346.000
100	42	1135.000	303790.000	-302655.000
100	43	1135.000	278570.000	-277435.000
100	44	1135.000	278570.000	-277435.000
	Max	1135.000	425084.000	0.029
	Average	782.263	200853.552	-200071.289
	Min	0.925	0.952	-423949.000
	Std Dev	525.710	147476.129	146998.387

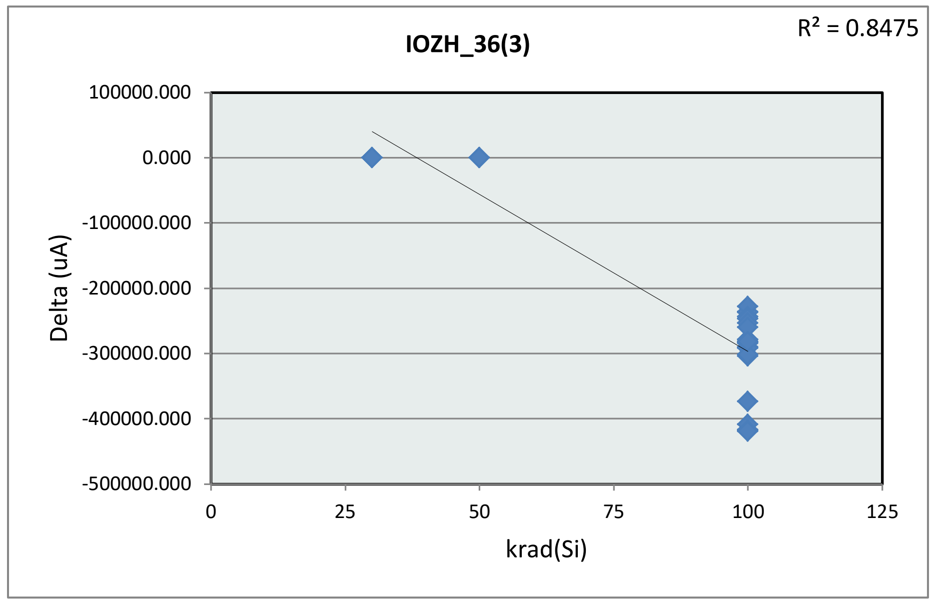


	IOZH_36(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.952	7.848	153673.000
Average	1.000	15.244	288177.652
Max	1.045	23.481	425084.000
UL	15.000	15.000	15.000

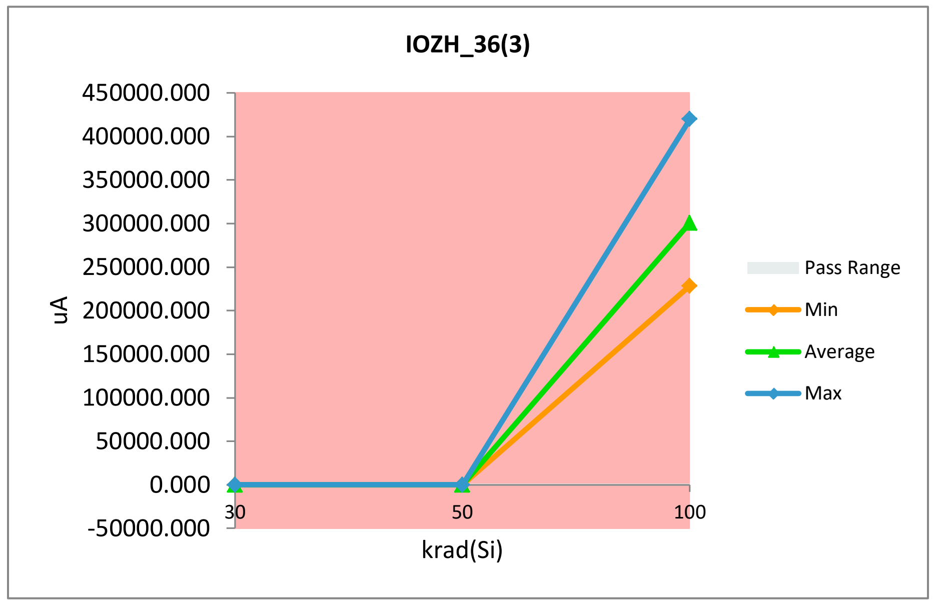


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZH_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.973	0.978	-0.005
30	2	0.935	0.922	0.013
30	3	0.973	0.978	-0.005
30	4	0.973	0.959	0.013
30	5	0.973	1.034	-0.061
50	11	0.898	24.270	-23.372
50	12	0.973	11.919	-10.946
50	13	0.973	13.124	-12.151
50	14	0.879	8.907	-8.028
50	15	0.973	15.836	-14.863
100	22	716.263	374199.000	-373482.737
100	23	716.263	417531.000	-416814.737
100	24	716.263	283924.000	-283207.737
100	25	716.263	409105.000	-408388.737
100	26	716.263	238185.000	-237468.737
100	27	716.263	236981.000	-236264.737
100	28	716.263	228555.000	-227838.737
100	29	716.263	279109.000	-278392.737
100	30	716.263	282720.000	-282003.737
100	31	716.263	418735.000	-418018.737
100	32	716.263	285128.000	-284411.737
100	33	716.263	244203.000	-243486.737
100	34	716.263	247814.000	-247097.737
100	35	716.263	279109.000	-278392.737
100	36	716.263	304386.000	-303669.737
100	37	716.263	253832.000	-253115.737
100	38	716.263	261054.000	-260337.737
100	39	716.263	419938.000	-419221.737
100	40	716.263	291146.000	-290429.737
100	41	716.263	292350.000	-291633.737
100	42	716.263	301979.000	-301262.737
100	43	716.263	282720.000	-282003.737
100	44	716.263	282720.000	-282003.737
	Max	716.263	419938.000	0.013
	Average	499.502	209560.664	-209061.162
	Min	0.879	0.922	-419221.737
	Std Dev	333.831	149429.421	149115.990

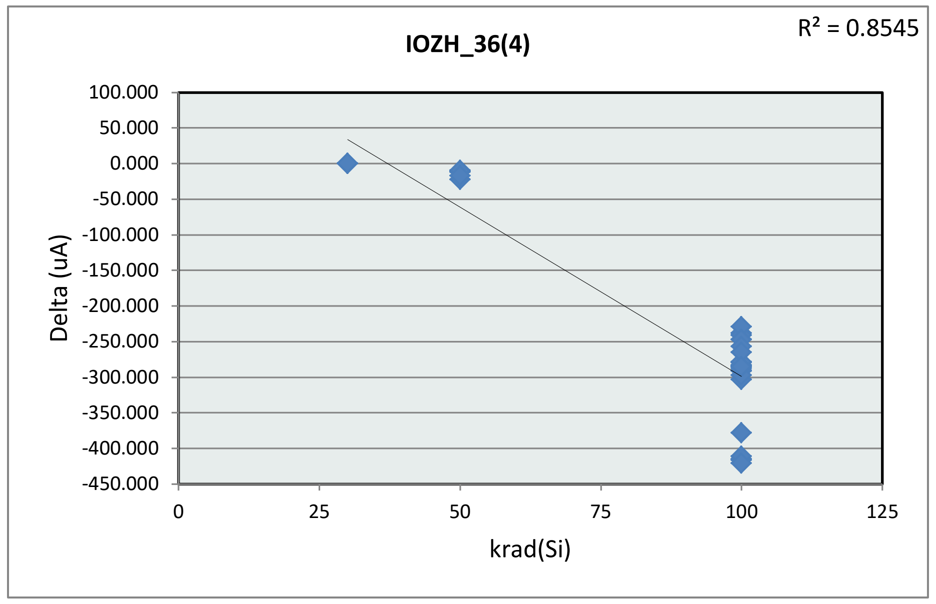


	IOZH_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.922	8.907	228555.000
Average	0.974	14.811	300670.565
Max	1.034	24.270	419938.000
UL	15.000	15.000	15.000

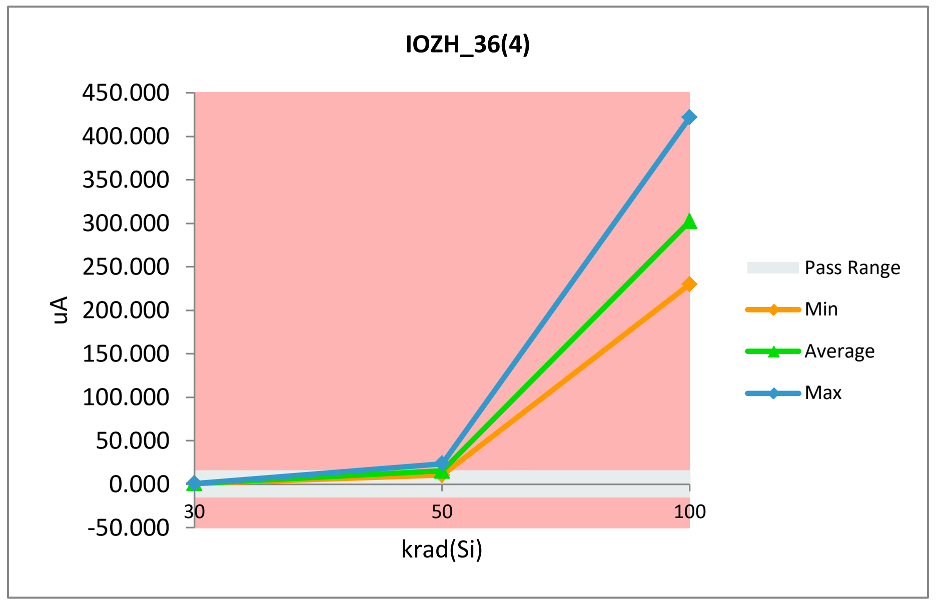


HDR TID Report T0 data
SN55LVCP22A-SP

		IOZH_36(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	0.985	1.011	-0.026
30	2	0.948	0.918	0.030
30	3	0.985	0.993	-0.007
30	4	0.985	0.974	0.012
30	5	0.985	1.123	-0.138
50	11	0.930	23.670	-22.740
50	12	0.985	12.262	-11.277
50	13	1.004	12.862	-11.858
50	14	0.911	10.461	-9.550
50	15	1.004	18.266	-17.262
100	22	0.919	378.900	-377.981
100	23	0.919	416.097	-415.178
100	24	0.919	285.307	-284.388
100	25	0.919	417.297	-416.378
100	26	1.219	239.711	-238.492
100	27	0.919	242.111	-241.192
100	28	1.219	230.112	-228.893
100	29	0.919	284.108	-283.189
100	30	0.919	280.508	-279.589
100	31	0.919	412.497	-411.578
100	32	1.219	288.907	-287.688
100	33	0.919	248.110	-247.191
100	34	1.219	248.110	-246.891
100	35	0.919	279.308	-278.389
100	36	1.219	304.506	-303.287
100	37	0.919	257.710	-256.791
100	38	0.919	266.109	-265.190
100	39	1.219	422.096	-420.877
100	40	1.219	292.507	-291.288
100	41	0.919	291.307	-290.388
100	42	0.919	298.507	-297.588
100	43	0.919	286.507	-285.588
100	44	0.919	286.507	-285.588
	Max	1.219	422.096	0.030
	Average	0.999	213.315	-212.316
	Min	0.911	0.918	-420.877
	Std Dev	0.120	146.518	146.508

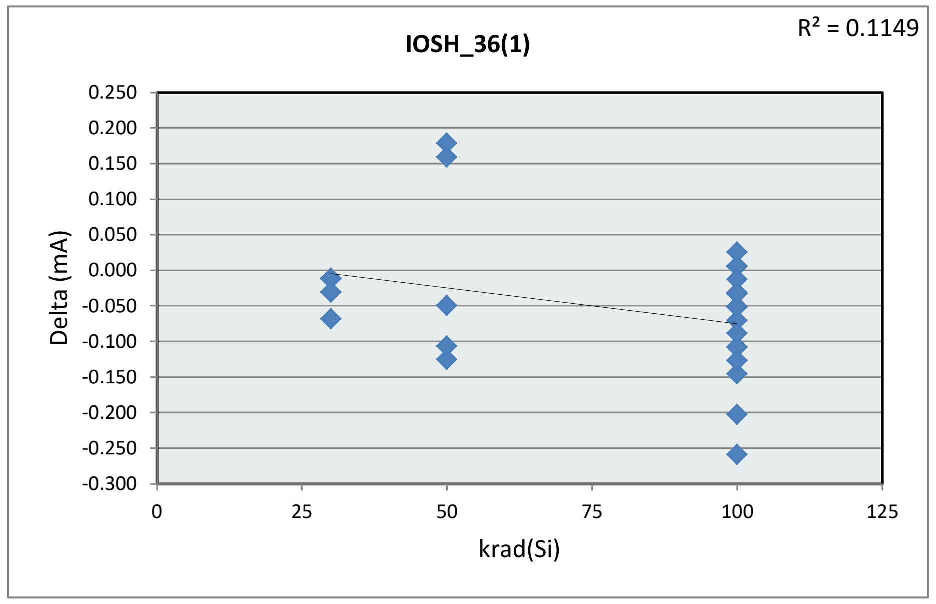


	IOZH_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.918	10.461	230.112
Average	1.004	15.504	302.471
Max	1.123	23.670	422.096
UL	15.000	15.000	15.000

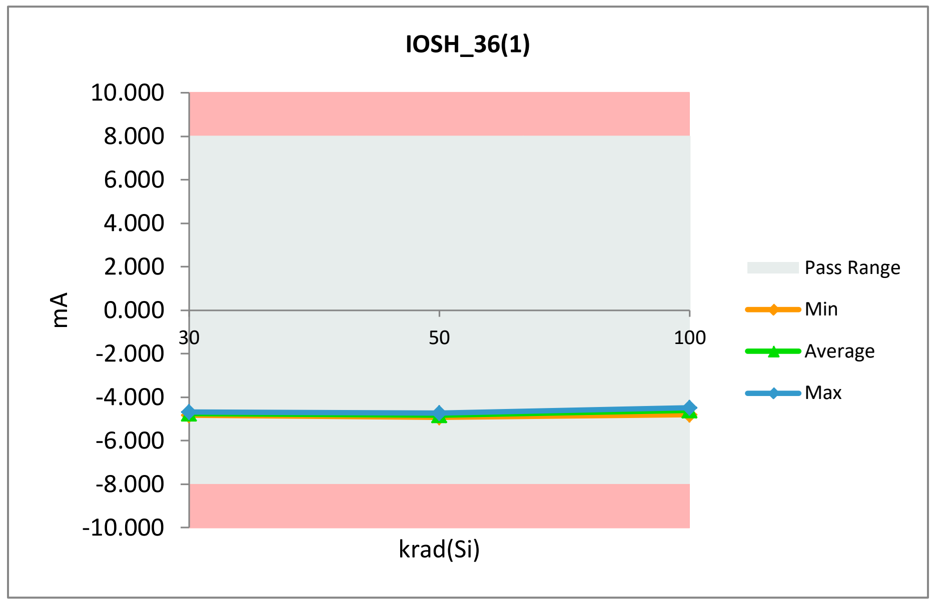


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSH_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-4.845	-4.834	-0.011
30	2	-4.713	-4.701	-0.012
30	3	-4.827	-4.796	-0.031
30	4	-4.713	-4.682	-0.031
30	5	-4.845	-4.777	-0.068
50	11	-4.940	-4.815	-0.125
50	12	-4.751	-4.929	0.178
50	13	-4.845	-4.739	-0.106
50	14	-4.808	-4.758	-0.050
50	15	-4.751	-4.910	0.159
100	22	-4.671	-4.544	-0.127
100	23	-4.784	-4.676	-0.108
100	24	-4.652	-4.581	-0.071
100	25	-4.727	-4.752	0.025
100	26	-4.841	-4.809	-0.032
100	27	-4.879	-4.733	-0.146
100	28	-4.803	-4.752	-0.051
100	29	-4.765	-4.657	-0.108
100	30	-4.519	-4.525	0.006
100	31	-4.614	-4.619	0.005
100	32	-4.576	-4.581	0.005
100	33	-4.727	-4.619	-0.108
100	34	-4.803	-4.544	-0.259
100	35	-4.727	-4.619	-0.108
100	36	-4.708	-4.600	-0.108
100	37	-4.822	-4.619	-0.203
100	38	-4.652	-4.525	-0.127
100	39	-4.519	-4.506	-0.013
100	40	-4.633	-4.581	-0.052
100	41	-4.595	-4.544	-0.051
100	42	-4.576	-4.487	-0.089
100	43	-4.671	-4.638	-0.033
100	44	-4.671	-4.638	-0.033
	Max	-4.519	-4.487	0.178
	Average	-4.726	-4.669	-0.057
	Min	-4.940	-4.929	-0.259
	Std Dev	0.106	0.117	0.085

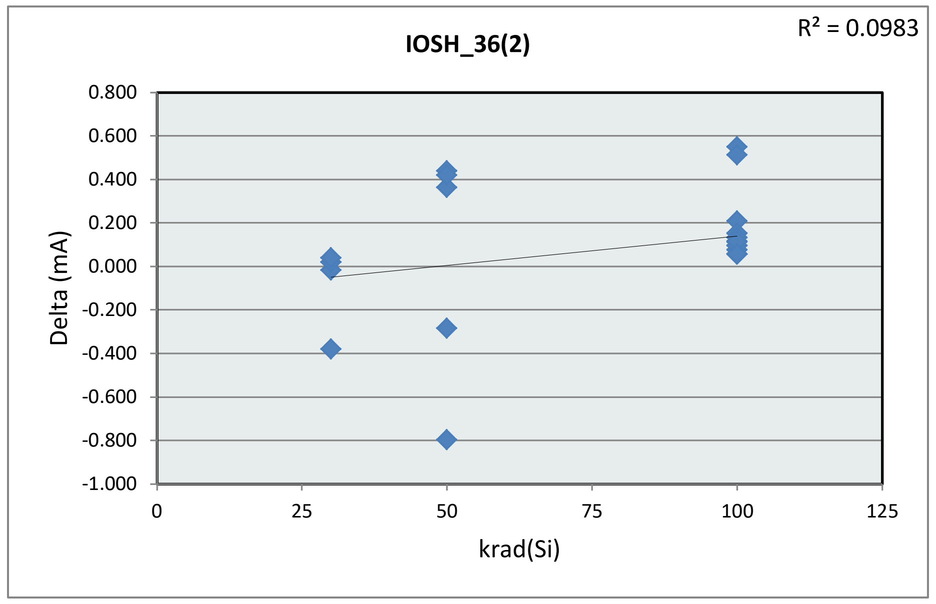


	IOSH_36(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.834	-4.929	-4.809
Average	-4.758	-4.830	-4.615
Max	-4.682	-4.739	-4.487
UL	8.000	8.000	8.000

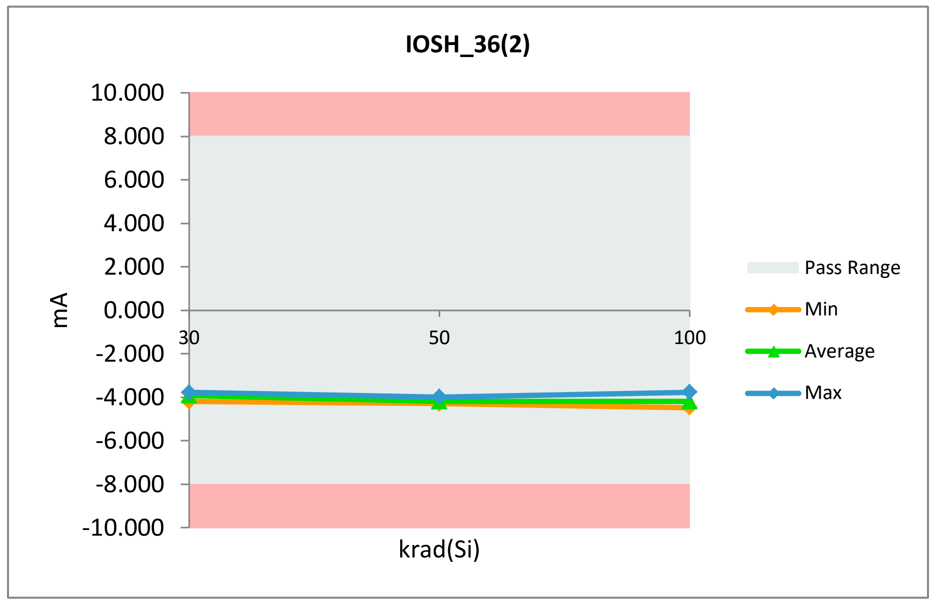


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	-3.839	-3.858	0.019
30	2	-4.218	-4.200	-0.018
30	3	-3.896	-3.915	0.019
30	4	-3.744	-3.782	0.038
30	5	-4.237	-3.858	-0.379
50	11	-4.275	-3.991	-0.284
50	12	-3.820	-4.257	0.437
50	13	-4.997	-4.200	-0.797
50	14	-3.839	-4.200	0.361
50	15	-3.877	-4.295	0.418
100	22	-3.723	-3.856	0.133
100	23	-4.274	-4.425	0.151
100	24	-3.723	-3.799	0.076
100	25	-4.312	-4.425	0.113
100	26	-4.274	-4.387	0.113
100	27	-4.331	-4.406	0.075
100	28	-3.894	-4.444	0.550
100	29	-3.742	-4.255	0.513
100	30	-3.704	-3.761	0.057
100	31	-3.913	-3.970	0.057
100	32	-4.160	-4.255	0.095
100	33	-4.198	-4.255	0.057
100	34	-4.274	-4.482	0.208
100	35	-4.198	-4.349	0.151
100	36	-3.818	-3.913	0.095
100	37	-4.274	-4.425	0.151
100	38	-3.951	-4.084	0.133
100	39	-4.065	-4.160	0.095
100	40	-3.761	-3.818	0.057
100	41	-4.198	-4.312	0.114
100	42	-4.103	-4.160	0.057
100	43	-4.160	-4.217	0.057
100	44	-4.160	-4.217	0.057
	Max	-3.704	-3.761	0.550
	Average	-4.059	-4.149	0.090
	Min	-4.997	-4.482	-0.797
	Std Dev	0.272	0.227	0.244



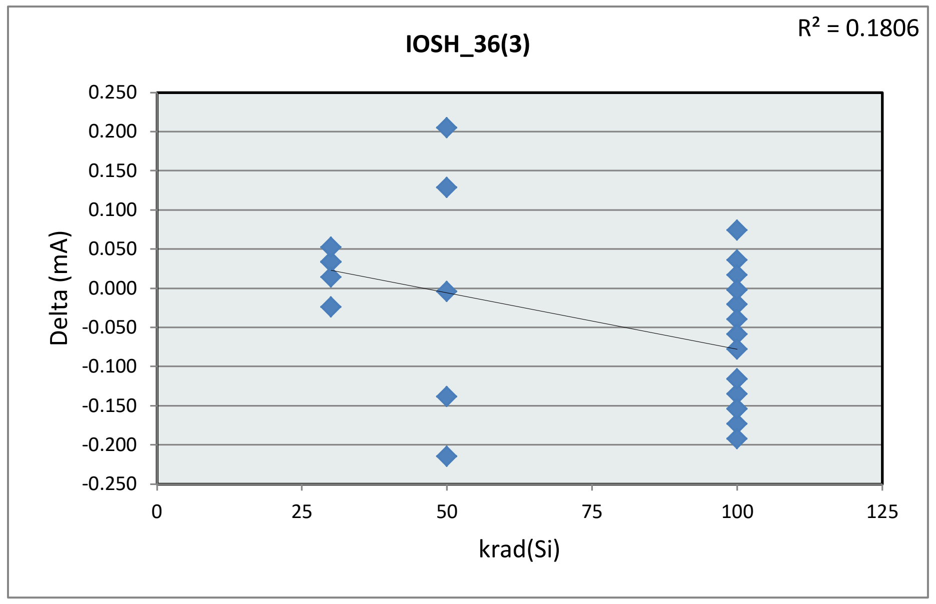
	IOSH_36(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.200	-4.295	-4.482
Average	-3.923	-4.189	-4.190
Max	-3.782	-3.991	-3.761
UL	8.000	8.000	8.000



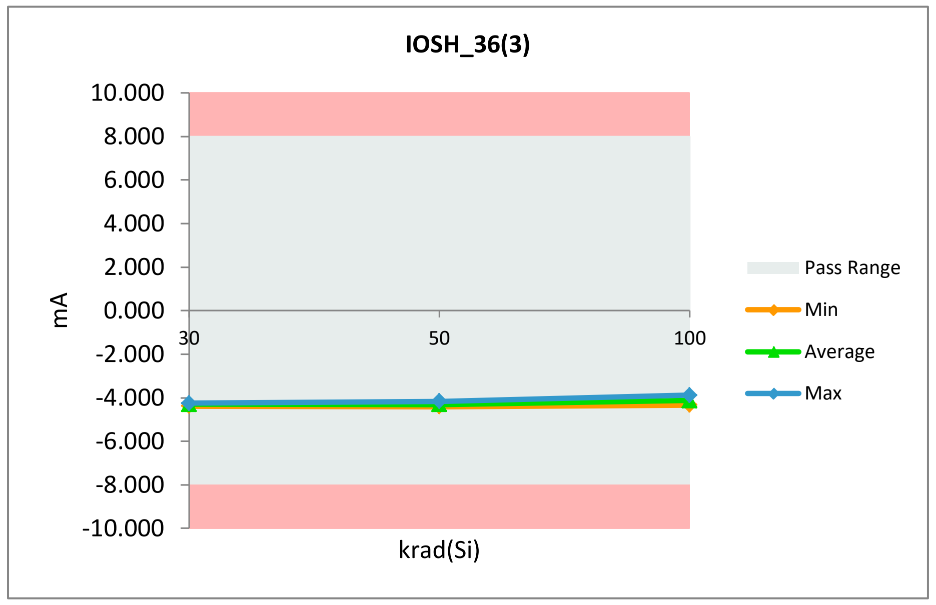
HDR TID Report T0 data
SN55LVCP22A-SP

	IOSH_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-4.240	-4.273	0.033
30	2	-4.278	-4.254	-0.024
30	3	-4.354	-4.388	0.034
30	4	-4.259	-4.273	0.014
30	5	-4.240	-4.292	0.052
50	11	-4.373	-4.235	-0.138
50	12	-4.164	-4.369	0.205
50	13	-4.373	-4.159	-0.214
50	14	-4.393	-4.388	-0.005
50	15	-4.278	-4.407	0.129
100	22	-4.096	-4.018	-0.078
100	23	-4.362	-4.189	-0.173
100	24	-4.210	-4.075	-0.135
100	25	-4.286	-4.170	-0.116
100	26	-4.286	-4.322	0.036
100	27	-4.362	-4.341	-0.021
100	28	-4.324	-4.208	-0.116
100	29	-4.077	-4.056	-0.021
100	30	-4.096	-4.037	-0.059
100	31	-4.096	-4.170	0.074
100	32	-4.381	-4.246	-0.135
100	33	-4.343	-4.303	-0.040
100	34	-4.172	-4.056	-0.116
100	35	-4.153	-3.999	-0.154
100	36	-4.267	-4.113	-0.154
100	37	-4.324	-4.132	-0.192
100	38	-4.343	-4.227	-0.116
100	39	-4.039	-3.885	-0.154
100	40	-4.134	-4.075	-0.059
100	41	-4.058	-3.980	-0.078
100	42	-4.058	-4.075	0.017
100	43	-4.134	-4.132	-0.002
100	44	-4.134	-4.132	-0.002
	Max	-4.039	-3.885	0.205
	Average	-4.233	-4.181	-0.052
	Min	-4.393	-4.407	-0.214
	Std Dev	0.113	0.133	0.096

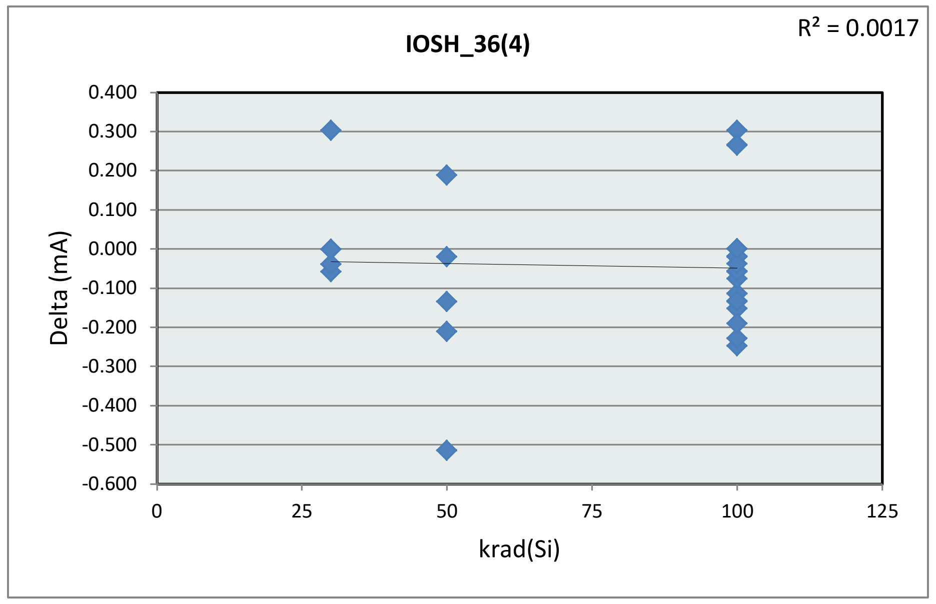


	IOSH_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.388	-4.407	-4.341
Average	-4.296	-4.312	-4.128
Max	-4.254	-4.159	-3.885
UL	8.000	8.000	8.000

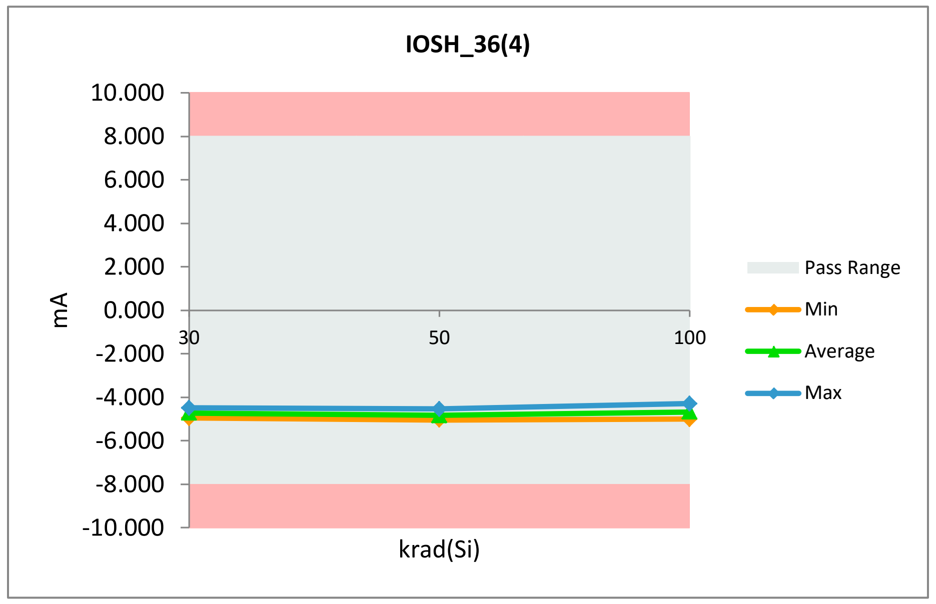


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSH_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-4.524	-4.523	-0.001
30	2	-4.961	-4.903	-0.058
30	3	-4.657	-4.960	0.303
30	4	-4.790	-4.751	-0.039
30	5	-4.486	-4.485	-0.001
50	11	-5.056	-4.542	-0.514
50	12	-4.847	-5.036	0.189
50	13	-4.999	-4.865	-0.134
50	14	-5.056	-5.036	-0.020
50	15	-4.866	-4.656	-0.210
100	22	-4.781	-4.648	-0.133
100	23	-5.047	-4.913	-0.134
100	24	-4.876	-4.762	-0.114
100	25	-4.515	-4.818	0.303
100	26	-5.028	-4.970	-0.058
100	27	-4.686	-4.572	-0.114
100	28	-4.990	-4.970	-0.020
100	29	-4.781	-4.762	-0.019
100	30	-4.401	-4.667	0.266
100	31	-4.838	-4.818	-0.020
100	32	-4.895	-4.743	-0.152
100	33	-5.028	-5.008	-0.020
100	34	-4.914	-4.667	-0.247
100	35	-4.515	-4.287	-0.228
100	36	-4.534	-4.344	-0.190
100	37	-4.933	-4.800	-0.133
100	38	-4.629	-4.894	0.265
100	39	-4.648	-4.591	-0.057
100	40	-4.363	-4.287	-0.076
100	41	-4.781	-4.724	-0.057
100	42	-4.344	-4.306	-0.038
100	43	-4.401	-4.401	0.000
100	44	-4.401	-4.401	0.000
	Max	-4.344	-4.287	0.303
	Average	-4.745	-4.700	-0.044
	Min	-5.056	-5.036	-0.514
	Std Dev	0.232	0.229	0.167



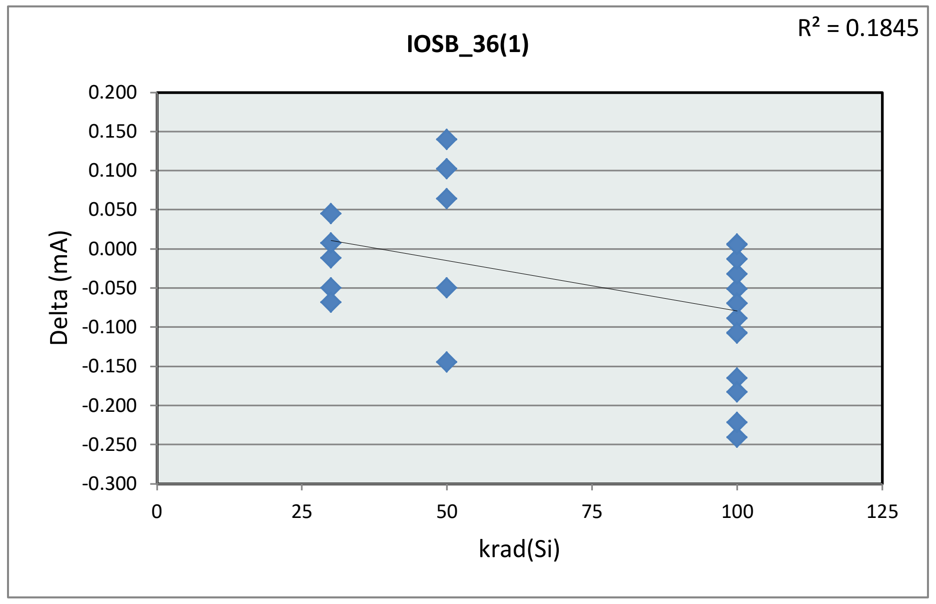
	IOSH_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.960	-5.036	-5.008
Average	-4.724	-4.827	-4.668
Max	-4.485	-4.542	-4.287
UL	8.000	8.000	8.000



HDR TID Report T0 data
SN55LVCP22A-SP

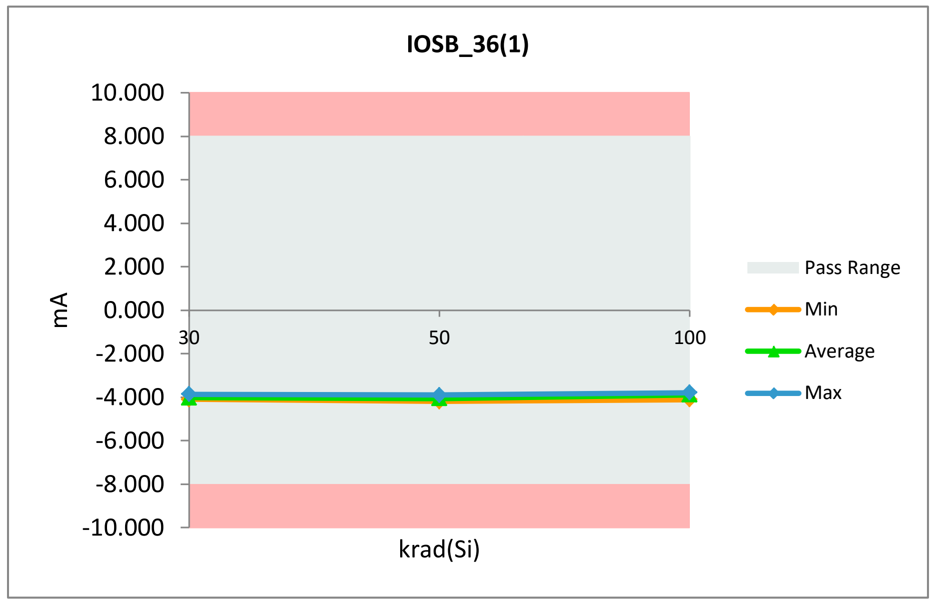
	IOSB_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-4.107	-4.095	-0.012
30	2	-3.917	-3.867	-0.050
30	3	-4.145	-4.076	-0.069
30	4	-3.993	-4.038	0.045
30	5	-4.050	-4.057	0.007
50	11	-4.088	-4.152	0.064
50	12	-3.898	-4.038	0.140
50	13	-4.145	-4.000	-0.145
50	14	-3.955	-3.905	-0.050
50	15	-4.088	-4.190	0.102
100	22	-3.874	-3.842	-0.032
100	23	-4.007	-3.937	-0.070
100	24	-3.950	-3.861	-0.089
100	25	-4.007	-3.956	-0.051
100	26	-4.159	-3.994	-0.165
100	27	-4.083	-3.975	-0.108
100	28	-4.140	-4.108	-0.032
100	29	-4.045	-3.975	-0.070
100	30	-3.837	-3.842	0.005
100	31	-3.969	-3.956	-0.013
100	32	-3.874	-3.861	-0.013
100	33	-3.893	-3.880	-0.013
100	34	-3.988	-3.805	-0.183
100	35	-4.121	-3.880	-0.241
100	36	-4.007	-3.918	-0.089
100	37	-4.102	-3.880	-0.222
100	38	-4.007	-3.824	-0.183
100	39	-3.893	-3.786	-0.107
100	40	-3.950	-3.880	-0.070
100	41	-3.818	-3.824	0.006
100	42	-3.856	-3.861	0.005
100	43	-3.856	-3.786	-0.070
100	44	-3.856	-3.786	-0.070
	Max	-3.818	-3.786	0.140
	Average	-3.990	-3.934	-0.056
	Min	-4.159	-4.190	-0.241
	Std Dev	0.104	0.111	0.086



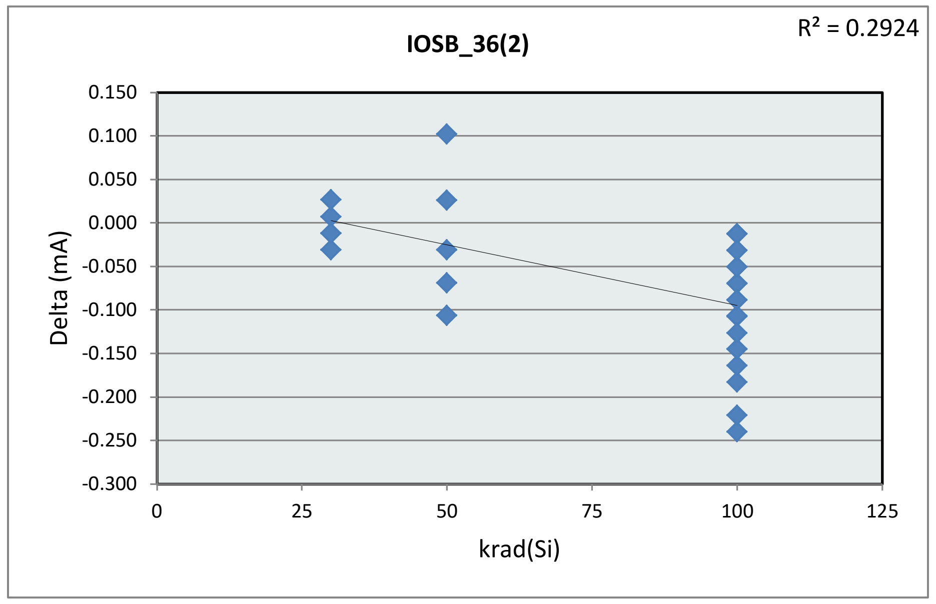
	IOSB_36(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.095	-4.190	-4.108
Average	-4.027	-4.057	-3.888
Max	-3.867	-3.905	-3.786
UL	8.000	8.000	8.000

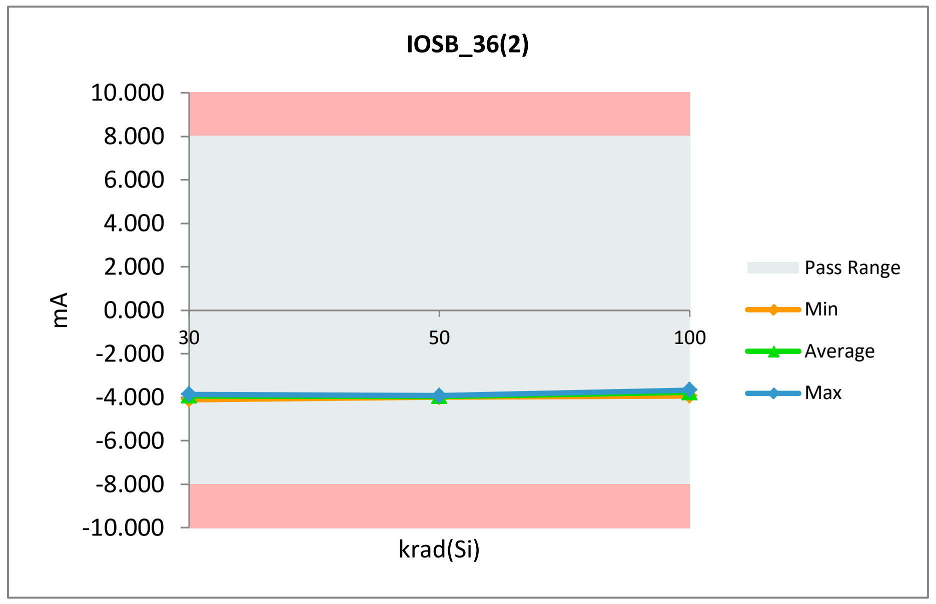


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSB_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-3.917	-3.924	0.007
30	2	-3.879	-3.867	-0.012
30	3	-4.088	-4.114	0.026
30	4	-3.898	-3.867	-0.031
30	5	-3.936	-3.924	-0.012
50	11	-4.012	-3.981	-0.031
50	12	-3.898	-4.000	0.102
50	13	-3.993	-3.924	-0.069
50	14	-3.898	-3.924	0.026
50	15	-4.107	-4.000	-0.107
100	22	-3.780	-3.691	-0.089
100	23	-3.893	-3.786	-0.107
100	24	-3.818	-3.710	-0.108
100	25	-3.931	-3.824	-0.107
100	26	-3.988	-3.918	-0.070
100	27	-3.969	-3.899	-0.070
100	28	-4.007	-3.937	-0.070
100	29	-3.912	-3.899	-0.013
100	30	-3.950	-3.710	-0.240
100	31	-3.856	-3.805	-0.051
100	32	-3.780	-3.767	-0.013
100	33	-3.874	-3.861	-0.013
100	34	-3.912	-3.729	-0.183
100	35	-3.931	-3.767	-0.164
100	36	-3.912	-3.767	-0.145
100	37	-3.950	-3.805	-0.145
100	38	-3.837	-3.710	-0.127
100	39	-3.761	-3.672	-0.089
100	40	-3.950	-3.729	-0.221
100	41	-3.799	-3.748	-0.051
100	42	-3.742	-3.691	-0.051
100	43	-3.818	-3.786	-0.032
100	44	-3.818	-3.786	-0.032
	Max	-3.742	-3.672	0.102
	Average	-3.903	-3.834	-0.069
	Min	-4.107	-4.114	-0.240
	Std Dev	0.087	0.109	0.073

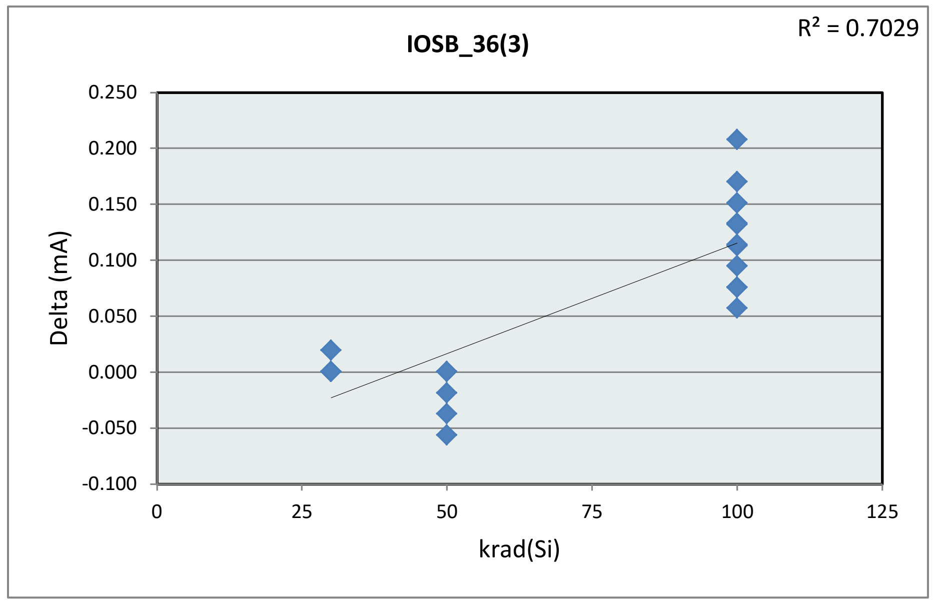


	IOSB_36(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.114	-4.000	-3.937
Average	-3.939	-3.966	-3.782
Max	-3.867	-3.924	-3.672
UL	8.000	8.000	8.000

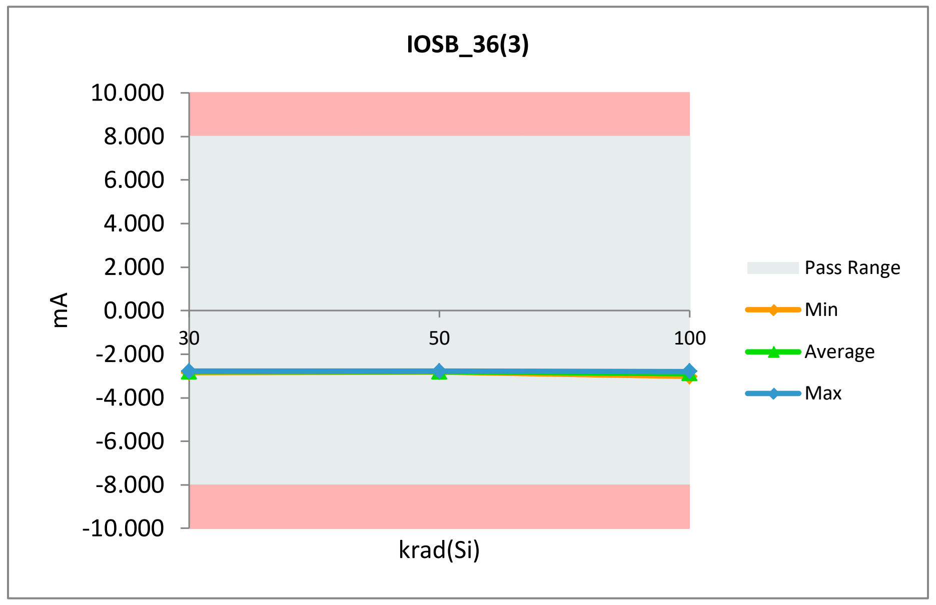


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSB_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-2.813	-2.814	0.001
30	2	-2.794	-2.795	0.001
30	3	-2.851	-2.852	0.001
30	4	-2.756	-2.776	0.020
30	5	-2.813	-2.814	0.001
50	11	-2.832	-2.776	-0.056
50	12	-2.813	-2.814	0.001
50	13	-2.832	-2.795	-0.037
50	14	-2.794	-2.776	-0.018
50	15	-2.832	-2.833	0.001
100	22	-2.755	-2.888	0.133
100	23	-2.831	-2.963	0.132
100	24	-2.717	-2.850	0.133
100	25	-2.850	-2.982	0.132
100	26	-2.793	-2.906	0.113
100	27	-2.831	-2.944	0.113
100	28	-2.812	-2.925	0.113
100	29	-2.736	-2.831	0.095
100	30	-2.736	-2.850	0.114
100	31	-2.736	-2.812	0.076
100	32	-2.755	-2.831	0.076
100	33	-2.755	-2.812	0.057
100	34	-2.812	-3.020	0.208
100	35	-2.793	-2.963	0.170
100	36	-2.812	-2.963	0.151
100	37	-2.793	-2.963	0.170
100	38	-2.755	-2.906	0.151
100	39	-2.698	-2.793	0.095
100	40	-2.755	-2.869	0.114
100	41	-2.755	-2.869	0.114
100	42	-2.717	-2.812	0.095
100	43	-2.755	-2.831	0.076
100	44	-2.755	-2.831	0.076
	Max	-2.698	-2.776	0.208
	Average	-2.783	-2.862	0.079
	Min	-2.851	-3.020	-0.056
	Std Dev	0.042	0.069	0.067



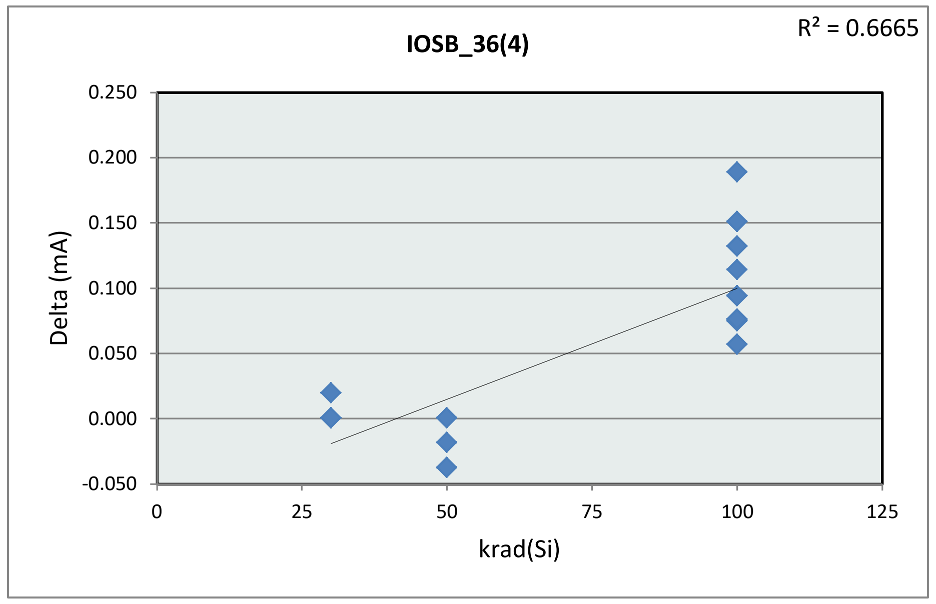
	IOSB_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-2.852	-2.833	-3.020
Average	-2.810	-2.799	-2.888
Max	-2.776	-2.776	-2.793
UL	8.000	8.000	8.000



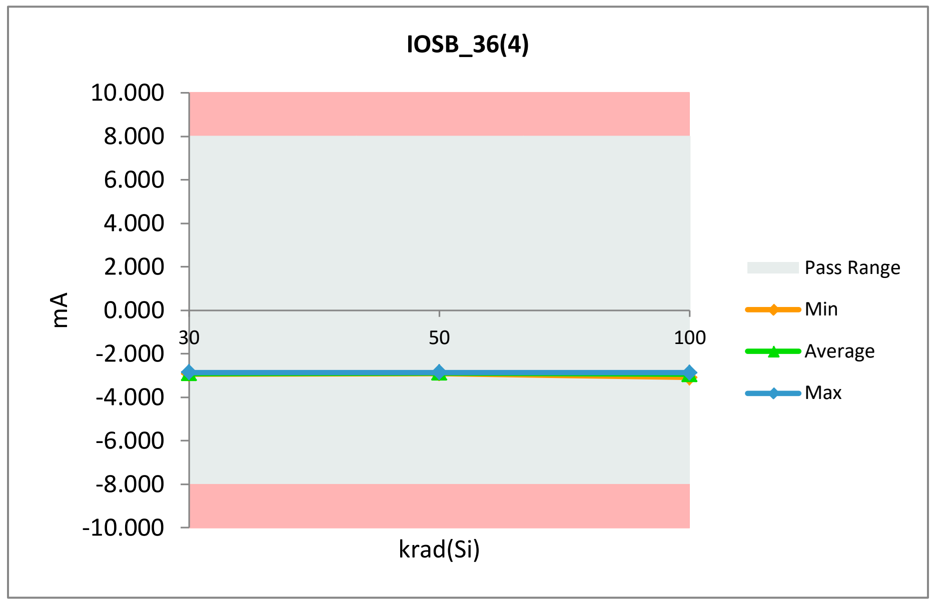
HDR TID Report T0 data
SN55LVCP22A-SP

	IOSB_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal	Delta
30	1	-2.908	-2.909	0.001
30	2	-2.889	-2.890	0.001
30	3	-2.927	-2.928	0.001
30	4	-2.851	-2.852	0.001
30	5	-2.908	-2.928	0.020
50	11	-2.889	-2.852	-0.037
50	12	-2.889	-2.890	0.001
50	13	-2.908	-2.890	-0.018
50	14	-2.889	-2.852	-0.037
50	15	-2.908	-2.909	0.001
100	22	-2.812	-2.944	0.132
100	23	-2.888	-3.020	0.132
100	24	-2.812	-2.906	0.094
100	25	-2.926	-3.020	0.094
100	26	-2.869	-2.963	0.094
100	27	-2.926	-3.001	0.075
100	28	-2.907	-3.001	0.094
100	29	-2.793	-2.869	0.076
100	30	-2.812	-2.888	0.076
100	31	-2.812	-2.888	0.076
100	32	-2.831	-2.906	0.075
100	33	-2.812	-2.888	0.076
100	34	-2.907	-3.096	0.189
100	35	-2.850	-3.001	0.151
100	36	-2.888	-3.020	0.132
100	37	-2.888	-3.039	0.151
100	38	-2.812	-2.963	0.151
100	39	-2.755	-2.869	0.114
100	40	-2.850	-2.925	0.075
100	41	-2.850	-2.944	0.094
100	42	-2.793	-2.869	0.076
100	43	-2.831	-2.888	0.057
100	44	-2.831	-2.888	0.057
	Max	-2.755	-2.852	0.189
	Average	-2.861	-2.930	0.069
	Min	-2.927	-3.096	-0.037
	Std Dev	0.047	0.063	0.059

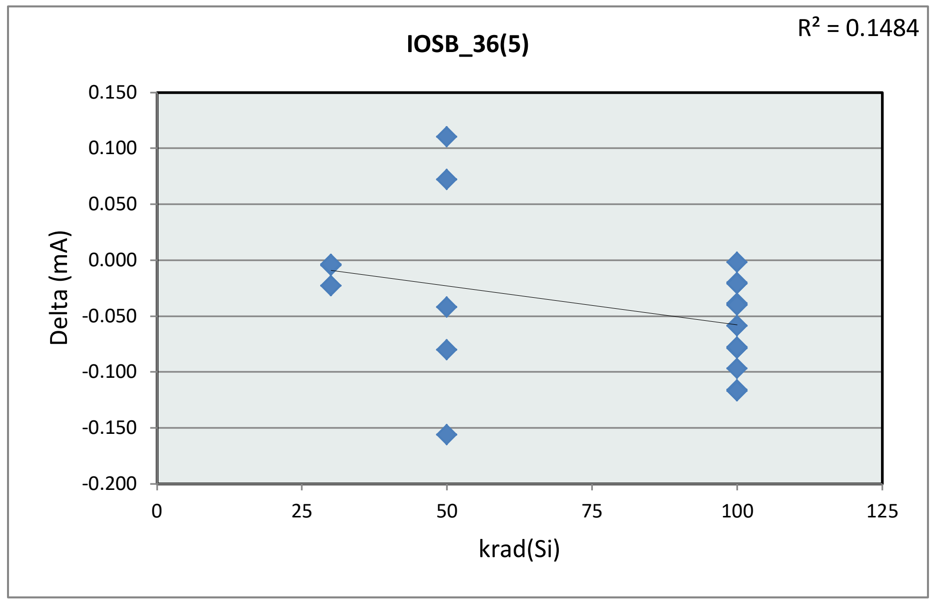


	IOSB_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-2.928	-2.909	-3.096
Average	-2.901	-2.879	-2.948
Max	-2.852	-2.852	-2.869
UL	8.000	8.000	8.000

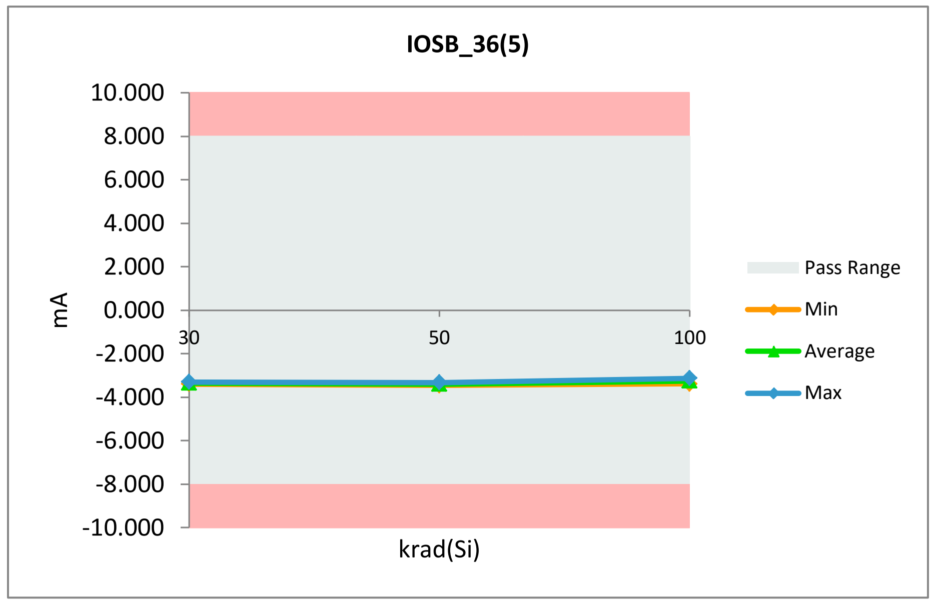


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSB_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-3.307	-3.302	-0.005
30	2	-3.402	-3.379	-0.023
30	3	-3.421	-3.398	-0.023
30	4	-3.326	-3.322	-0.004
30	5	-3.326	-3.322	-0.004
50	11	-3.478	-3.322	-0.156
50	12	-3.345	-3.455	0.110
50	13	-3.421	-3.341	-0.080
50	14	-3.497	-3.455	-0.042
50	15	-3.364	-3.436	0.072
100	22	-3.258	-3.142	-0.116
100	23	-3.411	-3.314	-0.097
100	24	-3.316	-3.237	-0.079
100	25	-3.296	-3.257	-0.039
100	26	-3.392	-3.352	-0.040
100	27	-3.373	-3.352	-0.021
100	28	-3.354	-3.295	-0.059
100	29	-3.239	-3.199	-0.040
100	30	-3.296	-3.257	-0.039
100	31	-3.277	-3.257	-0.020
100	32	-3.335	-3.257	-0.078
100	33	-3.430	-3.390	-0.040
100	34	-3.316	-3.199	-0.117
100	35	-3.316	-3.199	-0.117
100	36	-3.316	-3.237	-0.079
100	37	-3.316	-3.237	-0.079
100	38	-3.373	-3.295	-0.078
100	39	-3.182	-3.123	-0.059
100	40	-3.239	-3.237	-0.002
100	41	-3.239	-3.180	-0.059
100	42	-3.201	-3.161	-0.040
100	43	-3.316	-3.295	-0.021
100	44	-3.316	-3.295	-0.021
	Max	-3.182	-3.123	0.110
	Average	-3.333	-3.288	-0.045
	Min	-3.497	-3.455	-0.156
	Std Dev	0.074	0.086	0.052

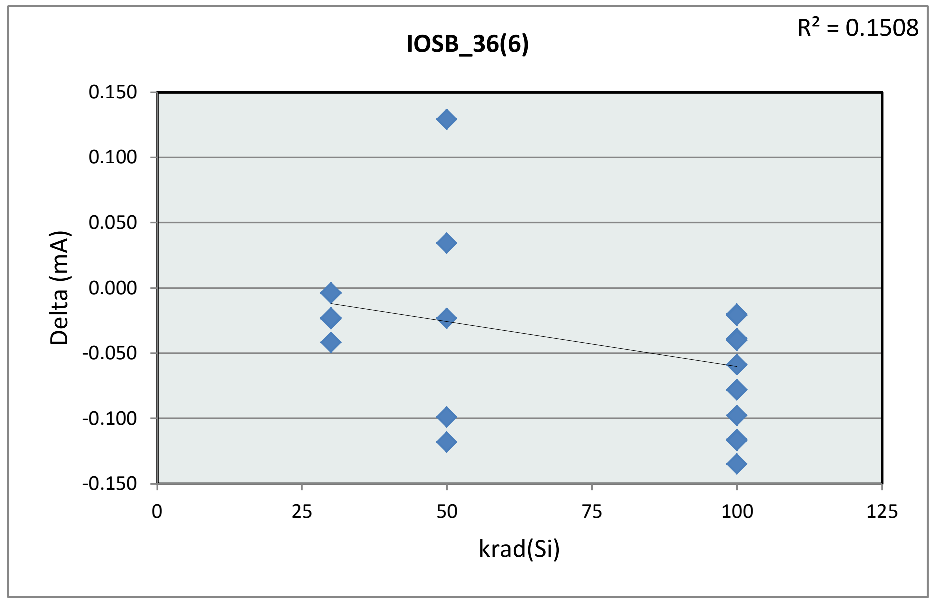


	IOSB_36(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-3.398	-3.455	-3.390
Average	-3.345	-3.402	-3.251
Max	-3.302	-3.322	-3.123
UL	8.000	8.000	8.000

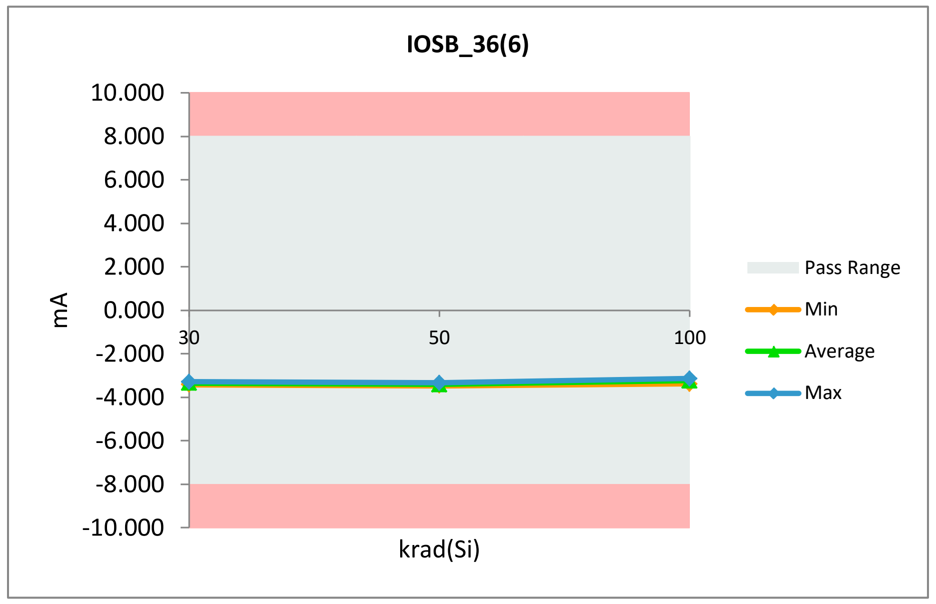


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSB_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-3.307	-3.283	-0.024
30	2	-3.421	-3.398	-0.023
30	3	-3.421	-3.417	-0.004
30	4	-3.326	-3.322	-0.004
30	5	-3.364	-3.322	-0.042
50	11	-3.459	-3.341	-0.118
50	12	-3.345	-3.474	0.129
50	13	-3.440	-3.341	-0.099
50	14	-3.478	-3.455	-0.023
50	15	-3.383	-3.417	0.034
100	22	-3.220	-3.142	-0.078
100	23	-3.411	-3.295	-0.116
100	24	-3.316	-3.218	-0.098
100	25	-3.277	-3.257	-0.020
100	26	-3.392	-3.333	-0.059
100	27	-3.392	-3.352	-0.040
100	28	-3.335	-3.314	-0.021
100	29	-3.239	-3.161	-0.078
100	30	-3.296	-3.218	-0.078
100	31	-3.296	-3.218	-0.078
100	32	-3.296	-3.257	-0.039
100	33	-3.430	-3.390	-0.040
100	34	-3.296	-3.161	-0.135
100	35	-3.316	-3.199	-0.117
100	36	-3.335	-3.257	-0.078
100	37	-3.296	-3.237	-0.059
100	38	-3.373	-3.295	-0.078
100	39	-3.182	-3.142	-0.040
100	40	-3.239	-3.218	-0.021
100	41	-3.220	-3.161	-0.059
100	42	-3.201	-3.180	-0.021
100	43	-3.316	-3.295	-0.021
100	44	-3.316	-3.295	-0.021
	Max	-3.182	-3.142	0.129
	Average	-3.331	-3.284	-0.048
	Min	-3.478	-3.474	-0.135
	Std Dev	0.076	0.092	0.050



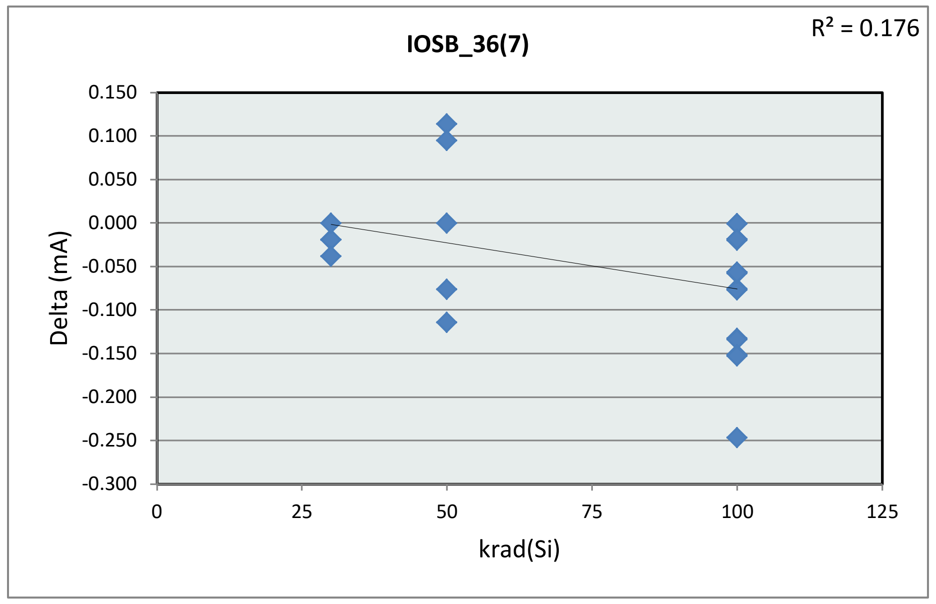
	IOSB_36(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-3.417	-3.474	-3.390
Average	-3.348	-3.406	-3.243
Max	-3.283	-3.341	-3.142
UL	8.000	8.000	8.000



HDR TID Report T0 data
SN55LVCP22A-SP

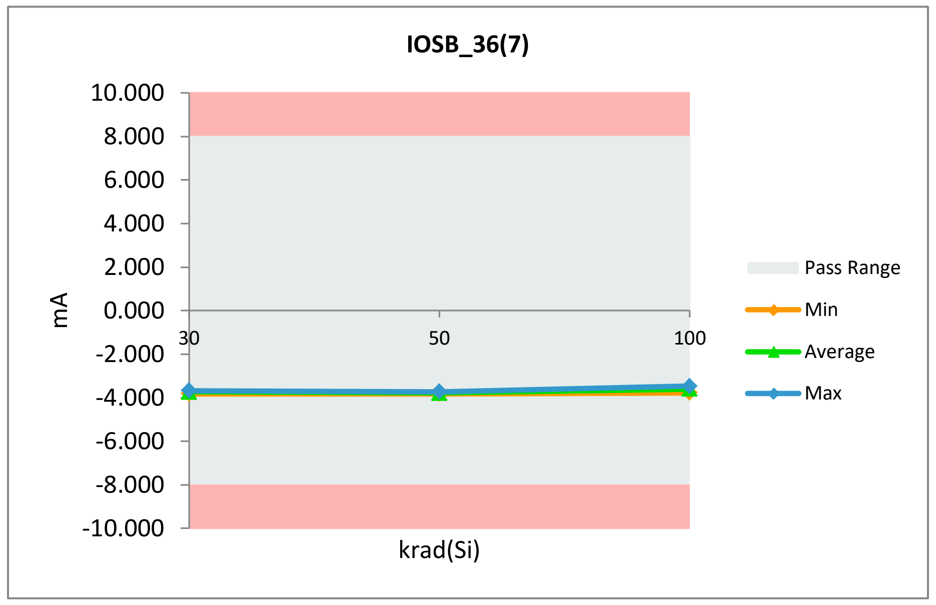
	IOSB_36(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-3.765	-3.745	-0.020
30	2	-3.727	-3.707	-0.020
30	3	-3.841	-3.821	-0.020
30	4	-3.708	-3.669	-0.039
30	5	-3.727	-3.726	-0.001
50	11	-3.822	-3.745	-0.077
50	12	-3.708	-3.821	0.113
50	13	-3.841	-3.726	-0.115
50	14	-3.803	-3.802	-0.001
50	15	-3.727	-3.821	0.094
100	22	-3.642	-3.509	-0.133
100	23	-3.775	-3.641	-0.134
100	24	-3.661	-3.585	-0.076
100	25	-3.737	-3.660	-0.077
100	26	-3.775	-3.774	-0.001
100	27	-3.851	-3.774	-0.077
100	28	-3.794	-3.736	-0.058
100	29	-3.623	-3.566	-0.057
100	30	-3.585	-3.566	-0.019
100	31	-3.642	-3.641	-0.001
100	32	-3.680	-3.660	-0.020
100	33	-3.737	-3.736	-0.001
100	34	-3.737	-3.490	-0.247
100	35	-3.680	-3.528	-0.152
100	36	-3.718	-3.566	-0.152
100	37	-3.737	-3.585	-0.152
100	38	-3.794	-3.641	-0.153
100	39	-3.528	-3.471	-0.057
100	40	-3.585	-3.528	-0.057
100	41	-3.585	-3.528	-0.057
100	42	-3.604	-3.547	-0.057
100	43	-3.604	-3.585	-0.019
100	44	-3.604	-3.585	-0.019
	Max	-3.528	-3.471	0.113
	Average	-3.707	-3.651	-0.056
	Min	-3.851	-3.821	-0.247
	Std Dev	0.086	0.106	0.072



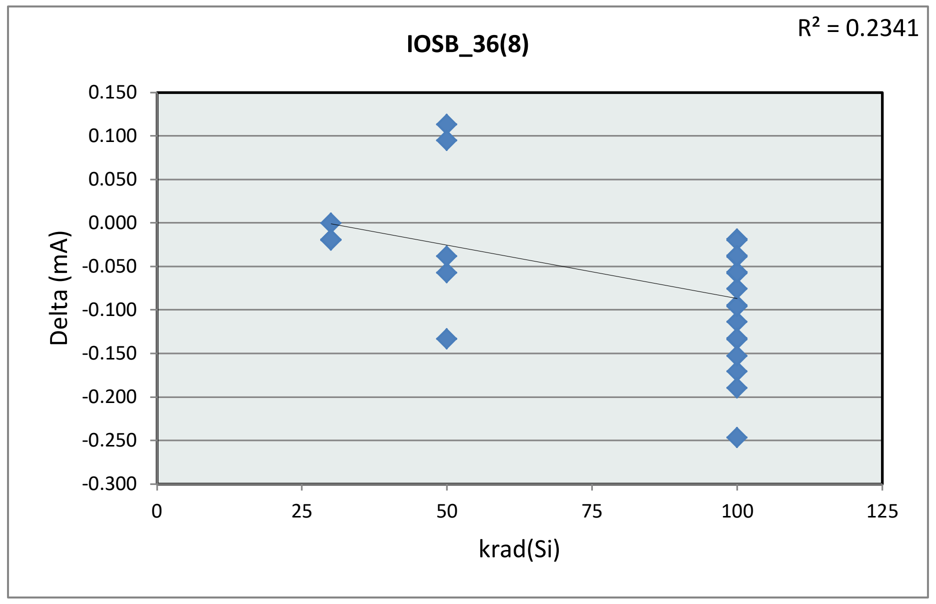
	IOSB_36(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-3.821	-3.821	-3.774
Average	-3.734	-3.783	-3.604
Max	-3.669	-3.726	-3.471
UL	8.000	8.000	8.000

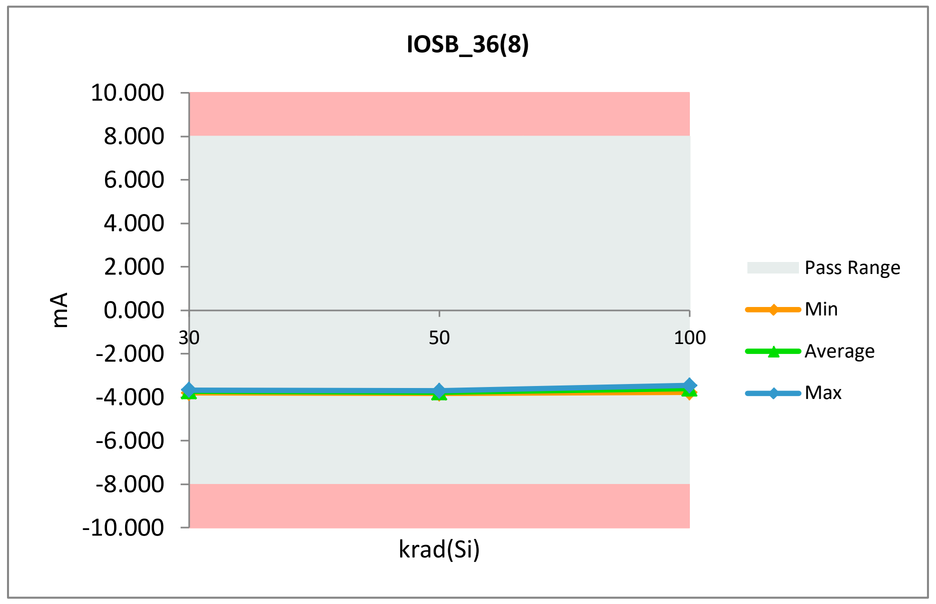


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSB_36(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-3.746	-3.745	-0.001
30	2	-3.708	-3.688	-0.020
30	3	-3.822	-3.802	-0.020
30	4	-3.689	-3.669	-0.020
30	5	-3.727	-3.707	-0.020
50	11	-3.822	-3.764	-0.058
50	12	-3.689	-3.802	0.113
50	13	-3.841	-3.707	-0.134
50	14	-3.822	-3.783	-0.039
50	15	-3.727	-3.821	0.094
100	22	-3.623	-3.509	-0.114
100	23	-3.794	-3.660	-0.134
100	24	-3.661	-3.566	-0.095
100	25	-3.756	-3.660	-0.096
100	26	-3.794	-3.755	-0.039
100	27	-3.832	-3.774	-0.058
100	28	-3.813	-3.717	-0.096
100	29	-3.623	-3.604	-0.019
100	30	-3.642	-3.585	-0.057
100	31	-3.642	-3.623	-0.019
100	32	-3.680	-3.660	-0.020
100	33	-3.775	-3.736	-0.039
100	34	-3.737	-3.490	-0.247
100	35	-3.699	-3.528	-0.171
100	36	-3.699	-3.566	-0.133
100	37	-3.756	-3.566	-0.190
100	38	-3.794	-3.641	-0.153
100	39	-3.528	-3.452	-0.076
100	40	-3.604	-3.547	-0.057
100	41	-3.604	-3.528	-0.076
100	42	-3.604	-3.547	-0.057
100	43	-3.604	-3.566	-0.038
100	44	-3.604	-3.566	-0.038
	Max	-3.528	-3.452	0.113
	Average	-3.711	-3.646	-0.064
	Min	-3.841	-3.821	-0.247
	Std Dev	0.085	0.103	0.072

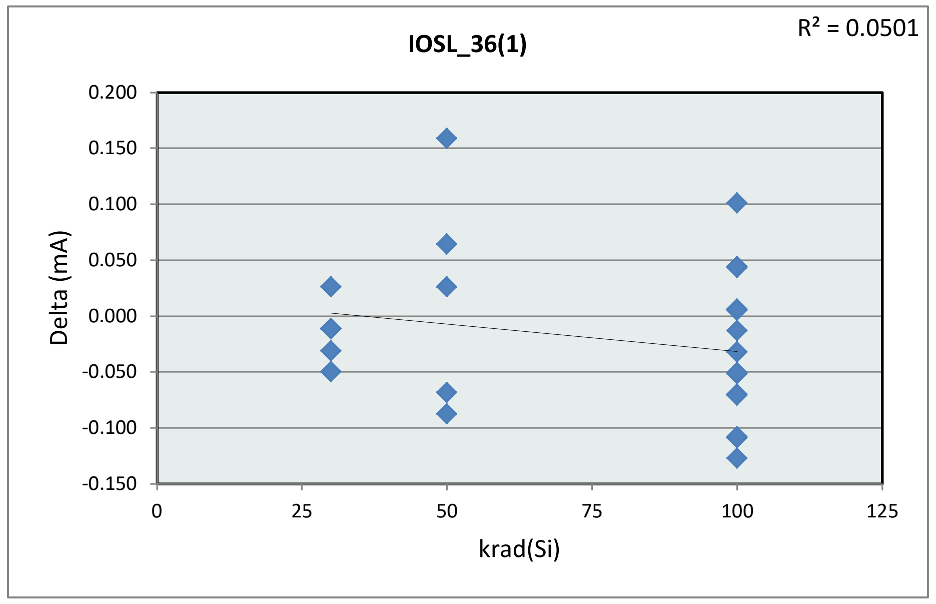


	IOSB_36(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-3.802	-3.821	-3.774
Average	-3.722	-3.775	-3.602
Max	-3.669	-3.707	-3.452
UL	8.000	8.000	8.000

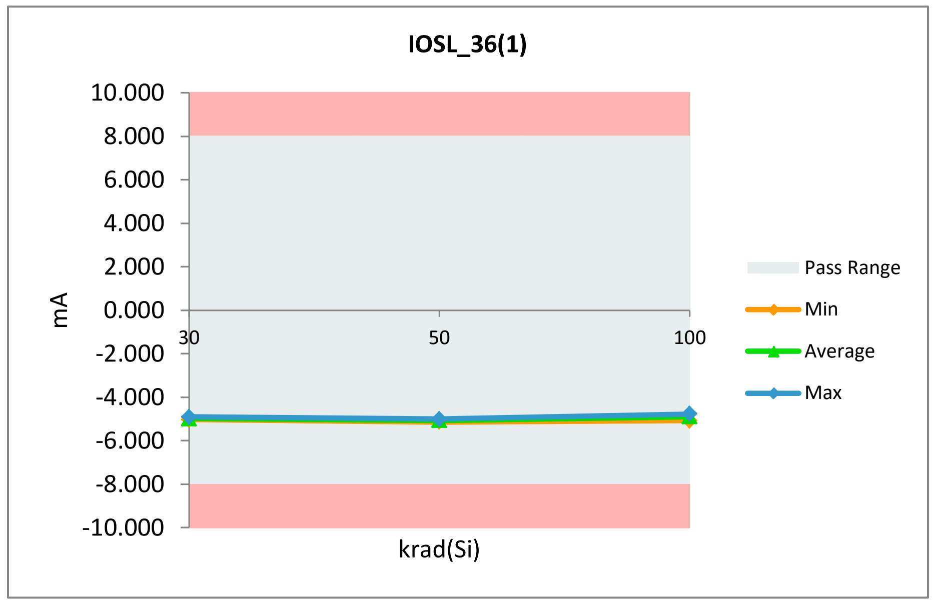


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-5.054	-5.004	-0.050
30	2	-4.978	-4.947	-0.031
30	3	-5.035	-5.023	-0.012
30	4	-4.921	-4.910	-0.011
30	5	-4.959	-4.985	0.026
50	11	-5.130	-5.061	-0.069
50	12	-4.978	-5.137	0.159
50	13	-5.092	-5.004	-0.088
50	14	-4.997	-5.023	0.026
50	15	-5.016	-5.080	0.064
100	22	-4.860	-4.828	-0.032
100	23	-5.031	-4.904	-0.127
100	24	-4.860	-4.809	-0.051
100	25	-5.012	-5.017	0.005
100	26	-5.050	-5.055	0.005
100	27	-5.069	-4.960	-0.109
100	28	-5.031	-5.074	0.043
100	29	-4.993	-4.941	-0.052
100	30	-4.746	-4.847	0.101
100	31	-4.917	-4.866	-0.051
100	32	-4.860	-4.828	-0.032
100	33	-4.974	-4.904	-0.070
100	34	-4.993	-4.885	-0.108
100	35	-4.993	-4.922	-0.071
100	36	-4.898	-4.885	-0.013
100	37	-5.012	-4.941	-0.071
100	38	-4.898	-4.790	-0.108
100	39	-4.822	-4.771	-0.051
100	40	-4.841	-4.847	0.006
100	41	-4.879	-4.847	-0.032
100	42	-4.746	-4.790	0.044
100	43	-4.860	-4.866	0.006
100	44	-4.860	-4.866	0.006
	Max	-4.746	-4.771	0.159
	Average	-4.950	-4.928	-0.023
	Min	-5.130	-5.137	-0.127
	Std Dev	0.096	0.096	0.062

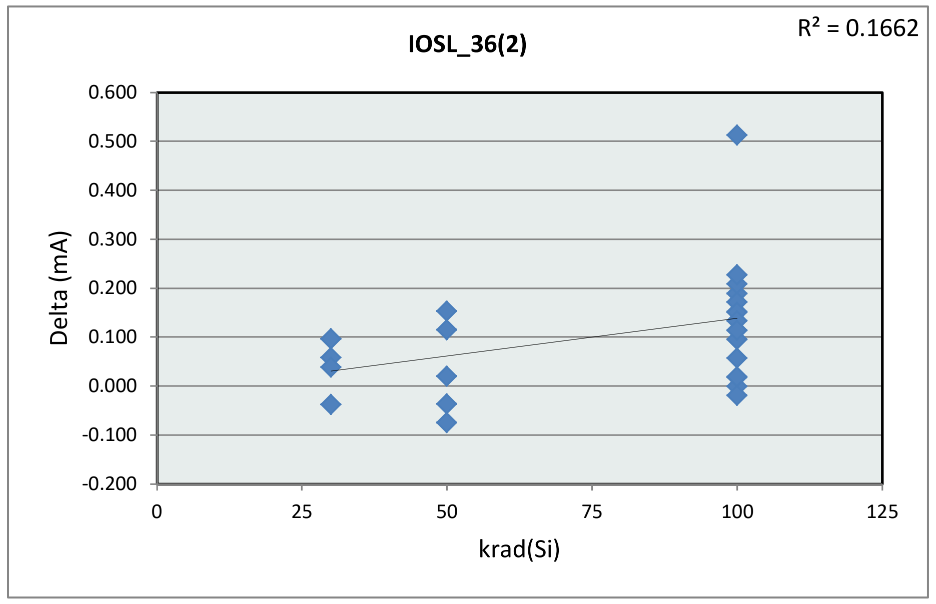


	IOSL_36(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-5.023	-5.137	-5.074
Average	-4.974	-5.061	-4.889
Max	-4.910	-5.004	-4.771
UL	8.000	8.000	8.000

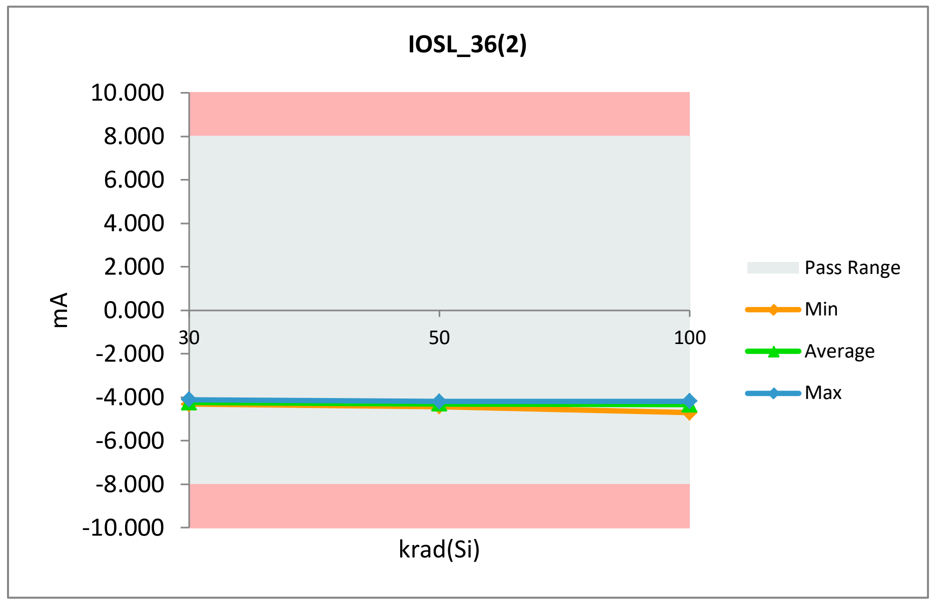


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-4.180	-4.238	0.058
30	2	-4.199	-4.238	0.039
30	3	-4.199	-4.295	0.096
30	4	-4.142	-4.105	-0.037
30	5	-4.218	-4.314	0.096
50	11	-4.332	-4.257	-0.075
50	12	-4.256	-4.276	0.020
50	13	-4.313	-4.428	0.115
50	14	-4.237	-4.200	-0.037
50	15	-4.180	-4.333	0.153
100	22	-4.160	-4.331	0.171
100	23	-4.388	-4.387	-0.001
100	24	-4.084	-4.236	0.152
100	25	-4.293	-4.444	0.151
100	26	-4.369	-4.387	0.018
100	27	-4.293	-4.312	0.019
100	28	-4.255	-4.444	0.189
100	29	-4.179	-4.368	0.189
100	30	-4.122	-4.255	0.133
100	31	-4.236	-4.293	0.057
100	32	-4.160	-4.331	0.171
100	33	-4.293	-4.274	-0.019
100	34	-4.293	-4.501	0.208
100	35	-4.198	-4.710	0.512
100	36	-4.179	-4.274	0.095
100	37	-4.236	-4.387	0.151
100	38	-4.179	-4.293	0.114
100	39	-4.065	-4.179	0.114
100	40	-4.198	-4.293	0.095
100	41	-4.179	-4.312	0.133
100	42	-4.084	-4.198	0.114
100	43	-4.141	-4.368	0.227
100	44	-4.141	-4.368	0.227
	Max	-4.065	-4.105	0.512
	Average	-4.212	-4.322	0.110
	Min	-4.388	-4.710	-0.075
	Std Dev	0.079	0.109	0.107

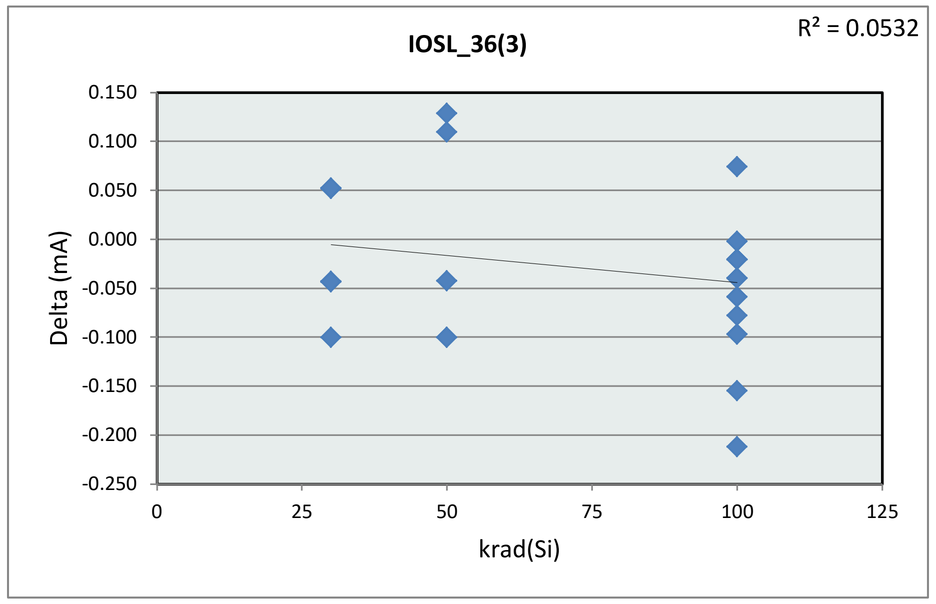


	IOSL_36(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.314	-4.428	-4.710
Average	-4.238	-4.299	-4.345
Max	-4.105	-4.200	-4.179
UL	8.000	8.000	8.000

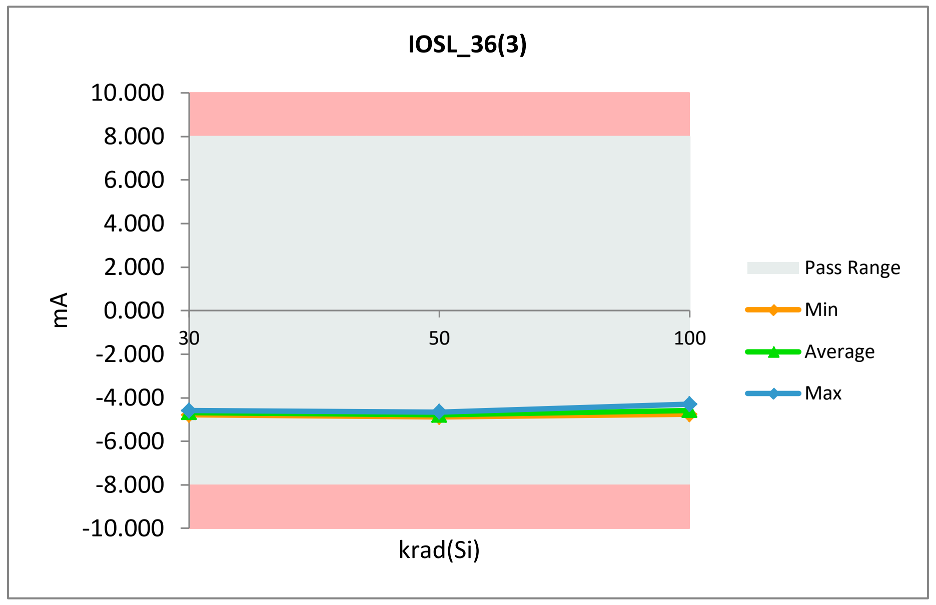


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-4.640	-4.597	-0.043
30	2	-4.812	-4.711	-0.101
30	3	-4.831	-4.787	-0.044
30	4	-4.621	-4.673	0.052
30	5	-4.602	-4.654	0.052
50	11	-4.812	-4.711	-0.101
50	12	-4.697	-4.826	0.129
50	13	-4.754	-4.654	-0.100
50	14	-4.888	-4.845	-0.043
50	15	-4.773	-4.883	0.110
100	22	-4.534	-4.494	-0.040
100	23	-4.781	-4.760	-0.021
100	24	-4.610	-4.551	-0.059
100	25	-4.572	-4.494	-0.078
100	26	-4.648	-4.722	0.074
100	27	-4.781	-4.760	-0.021
100	28	-4.743	-4.722	-0.021
100	29	-4.515	-4.513	-0.002
100	30	-4.572	-4.475	-0.097
100	31	-4.591	-4.570	-0.021
100	32	-4.629	-4.627	-0.002
100	33	-4.781	-4.722	-0.059
100	34	-4.591	-4.379	-0.212
100	35	-4.572	-4.551	-0.021
100	36	-4.686	-4.646	-0.040
100	37	-4.686	-4.589	-0.097
100	38	-4.762	-4.722	-0.040
100	39	-4.458	-4.303	-0.155
100	40	-4.534	-4.494	-0.040
100	41	-4.458	-4.437	-0.021
100	42	-4.496	-4.475	-0.021
100	43	-4.629	-4.608	-0.021
100	44	-4.629	-4.608	-0.021
	Max	-4.458	-4.303	0.129
	Average	-4.657	-4.623	-0.034
	Min	-4.888	-4.883	-0.212
	Std Dev	0.114	0.137	0.068

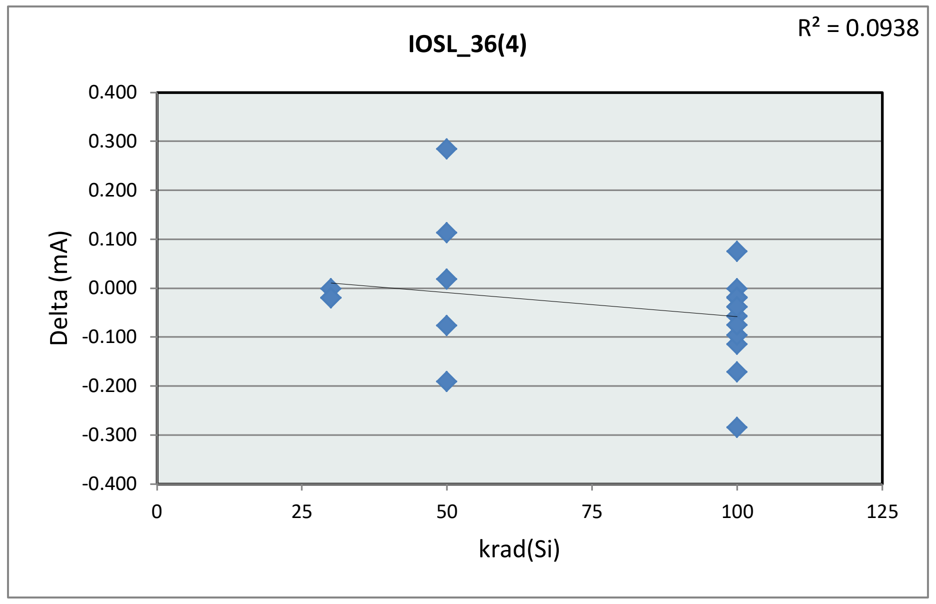


	IOSL_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-4.787	-4.883	-4.760
Average	-4.684	-4.784	-4.575
Max	-4.597	-4.654	-4.303
UL	8.000	8.000	8.000

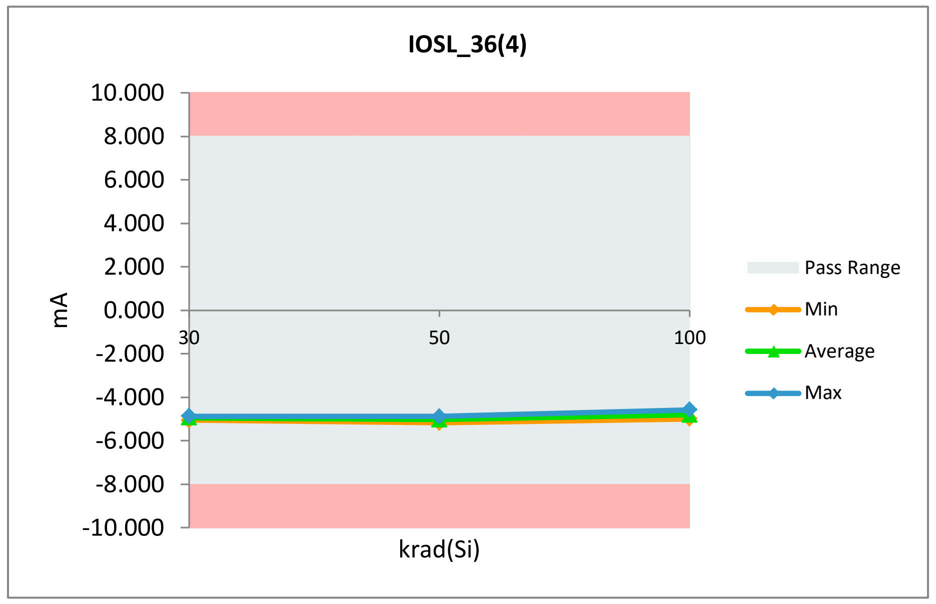


HDR TID Report T0 data
SN55LVCP22A-SP

		IOSL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal	Delta
30	1	-4.942	-4.922	-0.020
30	2	-4.942	-4.941	-0.001
30	3	-5.075	-5.055	-0.020
30	4	-4.885	-4.865	-0.020
30	5	-4.923	-4.903	-0.020
50	11	-5.037	-4.960	-0.077
50	12	-4.885	-5.169	0.284
50	13	-5.075	-4.884	-0.191
50	14	-5.056	-5.074	0.018
50	15	-4.942	-5.055	0.113
100	22	-4.819	-4.648	-0.171
100	23	-5.028	-4.913	-0.115
100	24	-4.952	-4.856	-0.096
100	25	-4.914	-4.856	-0.058
100	26	-4.971	-4.951	-0.020
100	27	-5.009	-4.989	-0.020
100	28	-4.990	-4.989	-0.001
100	29	-4.781	-4.705	-0.076
100	30	-4.762	-4.837	0.075
100	31	-4.819	-4.781	-0.038
100	32	-4.857	-4.818	-0.039
100	33	-4.990	-4.951	-0.039
100	34	-4.933	-4.648	-0.285
100	35	-4.876	-4.856	-0.020
100	36	-4.857	-4.800	-0.057
100	37	-4.933	-4.818	-0.115
100	38	-4.990	-4.894	-0.096
100	39	-4.648	-4.572	-0.076
100	40	-4.743	-4.705	-0.038
100	41	-4.724	-4.705	-0.019
100	42	-4.743	-4.724	-0.019
100	43	-4.800	-4.762	-0.038
100	44	-4.800	-4.762	-0.038
	Max	-4.648	-4.572	0.284
	Average	-4.900	-4.860	-0.040
	Min	-5.075	-5.169	-0.285
	Std Dev	0.110	0.136	0.092



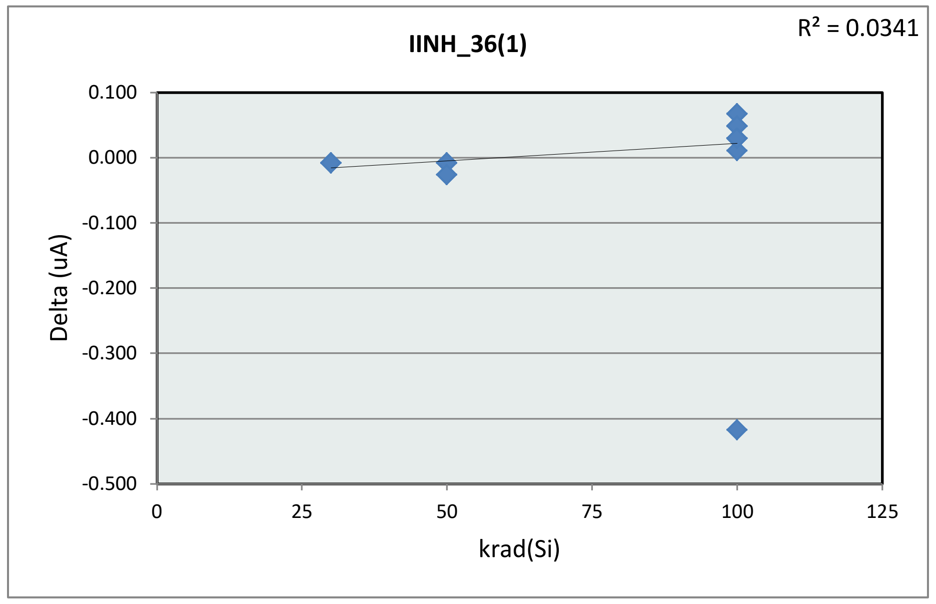
	IOSL_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	8	mA	
Min Limit	-8	mA	
krad(Si)	30	50	100
LL	-8.000	-8.000	-8.000
Min	-5.055	-5.169	-4.989
Average	-4.937	-5.028	-4.806
Max	-4.865	-4.884	-4.572
UL	8.000	8.000	8.000



HDR TID Report T0 data
SN55LVCP22A-SP

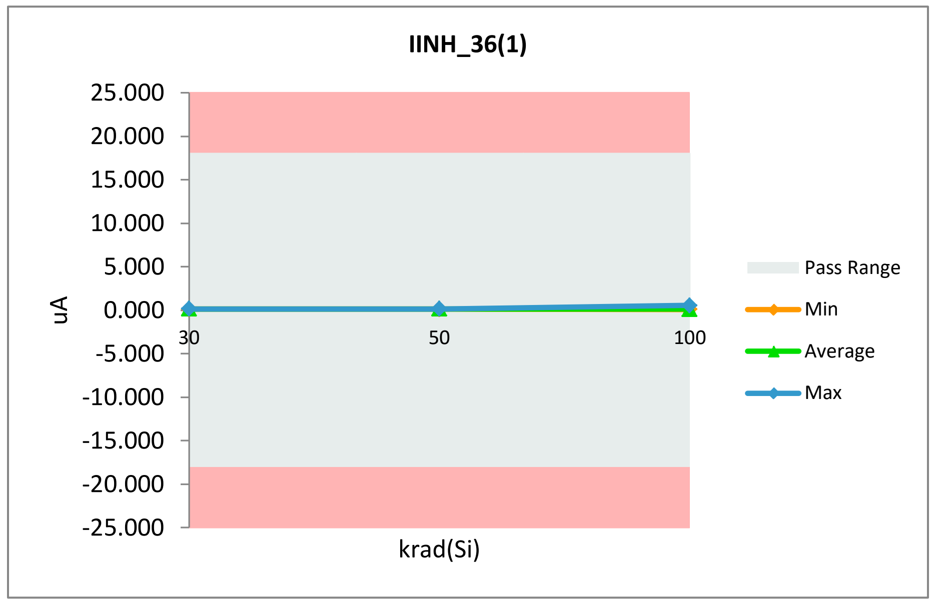
	IINH_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	0.143	0.151	-0.008
30	2	0.106	0.114	-0.008
30	3	0.143	0.151	-0.008
30	4	0.143	0.151	-0.008
30	5	0.125	0.133	-0.008
50	11	0.125	0.151	-0.027
50	12	0.125	0.133	-0.008
50	13	0.143	0.151	-0.008
50	14	0.143	0.151	-0.008
50	15	0.125	0.151	-0.027
100	22	0.130	0.081	0.048
100	23	0.130	0.081	0.048
100	24	0.148	0.100	0.048
100	25	0.148	0.100	0.048
100	26	0.148	0.137	0.011
100	27	0.148	0.119	0.029
100	28	0.148	0.100	0.048
100	29	0.148	0.566	-0.418
100	30	0.148	0.100	0.048
100	31	0.148	0.119	0.029
100	32	0.148	0.119	0.029
100	33	0.148	0.119	0.029
100	34	0.148	0.081	0.067
100	35	0.148	0.081	0.067
100	36	0.148	0.081	0.067
100	37	0.148	0.081	0.067
100	38	0.148	0.100	0.048
100	39	0.130	0.100	0.029
100	40	0.148	0.100	0.048
100	41	0.148	0.119	0.029
100	42	0.148	0.119	0.029
100	43	0.148	0.119	0.029
100	44	0.148	0.119	0.029
	Max	0.148	0.566	0.067
	Average	0.142	0.130	0.012
	Min	0.106	0.081	-0.418
	Std Dev	0.011	0.082	0.082



	IINH_36(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	18	uA
Min Limit	-18	uA

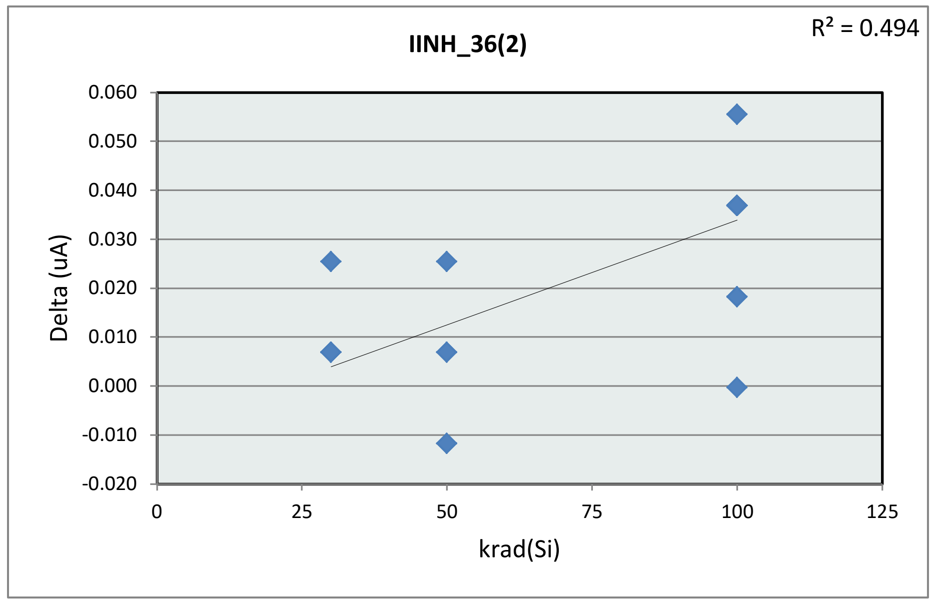
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.114	0.133	0.081
Average	0.140	0.148	0.124
Max	0.151	0.151	0.566
UL	18.000	18.000	18.000



HDR TID Report T0 data
SN55LVCP22A-SP

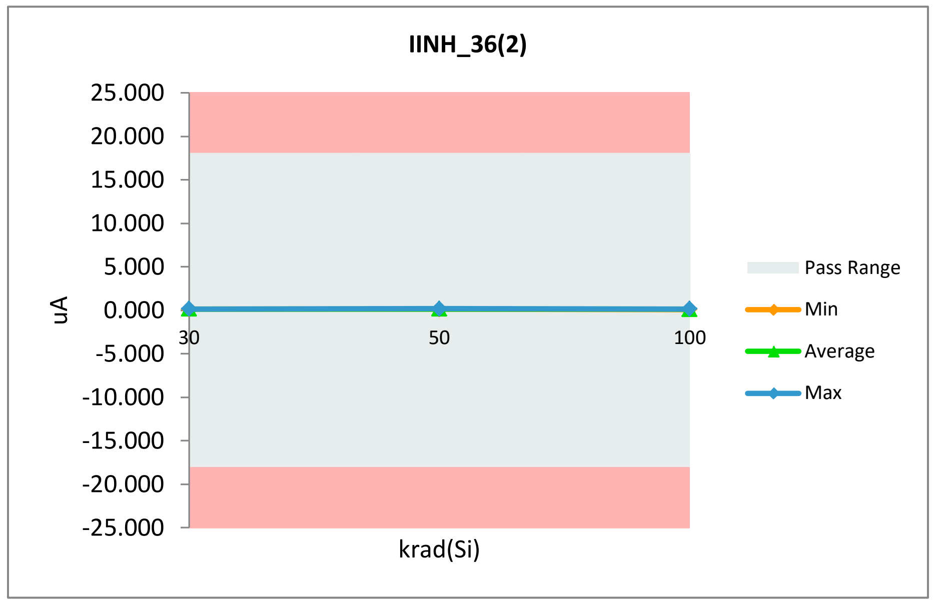
	IINH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	0.163	0.138	0.025
30	2	0.126	0.119	0.007
30	3	0.163	0.157	0.007
30	4	0.163	0.157	0.007
30	5	0.145	0.138	0.007
50	11	0.163	0.157	0.007
50	12	0.163	0.138	0.025
50	13	0.163	0.157	0.007
50	14	0.145	0.157	-0.012
50	15	0.163	0.175	-0.012
100	22	0.156	0.119	0.037
100	23	0.156	0.119	0.037
100	24	0.156	0.119	0.037
100	25	0.156	0.119	0.037
100	26	0.156	0.157	0.000
100	27	0.175	0.138	0.037
100	28	0.156	0.119	0.037
100	29	0.156	0.138	0.018
100	30	0.156	0.119	0.037
100	31	0.138	0.119	0.018
100	32	0.156	0.119	0.037
100	33	0.138	0.119	0.018
100	34	0.138	0.101	0.037
100	35	0.156	0.119	0.037
100	36	0.156	0.119	0.037
100	37	0.156	0.101	0.055
100	38	0.156	0.101	0.055
100	39	0.138	0.101	0.037
100	40	0.156	0.119	0.037
100	41	0.156	0.119	0.037
100	42	0.156	0.119	0.037
100	43	0.175	0.138	0.037
100	44	0.175	0.138	0.037
	Max	0.175	0.175	0.055
	Average	0.156	0.130	0.026
	Min	0.126	0.101	-0.012
	Std Dev	0.011	0.019	0.017



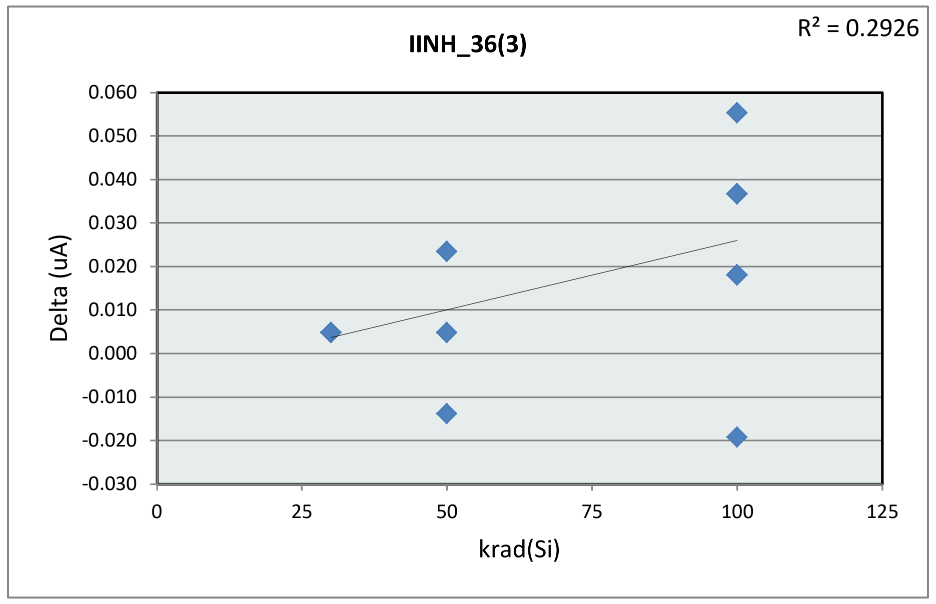
	IINH_36(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	18	uA
Min Limit	-18	uA

krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.119	0.138	0.101
Average	0.142	0.157	0.121
Max	0.157	0.175	0.157
UL	18.000	18.000	18.000

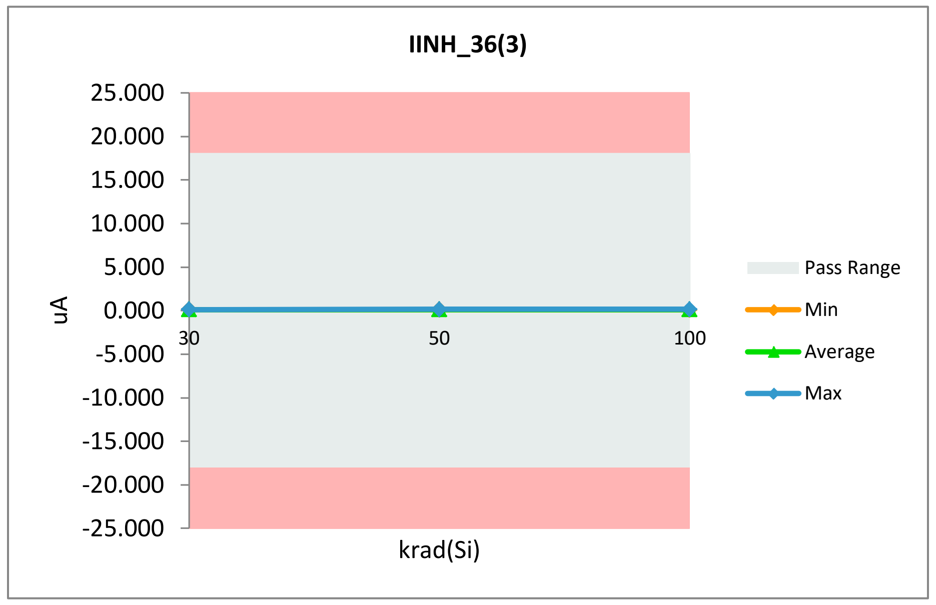


HDR TID Report T0 data
SN55LVCP22A-SP

		IINH_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	0.138	0.133	0.005
30	2	0.119	0.115	0.005
30	3	0.138	0.133	0.005
30	4	0.138	0.133	0.005
30	5	0.119	0.115	0.005
50	11	0.138	0.133	0.005
50	12	0.138	0.133	0.005
50	13	0.157	0.133	0.023
50	14	0.138	0.115	0.023
50	15	0.138	0.152	-0.014
100	22	0.119	0.101	0.018
100	23	0.138	0.101	0.037
100	24	0.138	0.120	0.018
100	25	0.157	0.120	0.037
100	26	0.138	0.157	-0.019
100	27	0.157	0.120	0.037
100	28	0.138	0.120	0.018
100	29	0.138	0.120	0.018
100	30	0.138	0.120	0.018
100	31	0.157	0.120	0.037
100	32	0.138	0.120	0.018
100	33	0.138	0.120	0.018
100	34	0.138	0.083	0.055
100	35	0.138	0.083	0.055
100	36	0.138	0.101	0.037
100	37	0.138	0.101	0.037
100	38	0.138	0.101	0.037
100	39	0.138	0.101	0.037
100	40	0.138	0.120	0.018
100	41	0.138	0.120	0.018
100	42	0.138	0.120	0.018
100	43	0.138	0.120	0.018
100	44	0.138	0.120	0.018
	Max	0.157	0.157	0.055
	Average	0.138	0.118	0.020
	Min	0.119	0.083	-0.019
	Std Dev	0.009	0.016	0.017

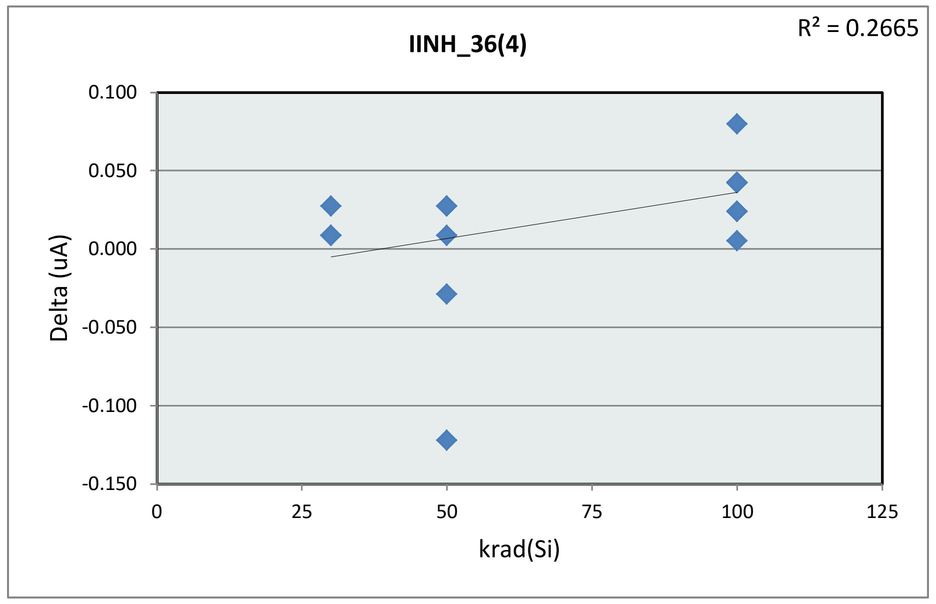


	IINH_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.115	0.115	0.083
Average	0.126	0.133	0.113
Max	0.133	0.152	0.157
UL	18.000	18.000	18.000

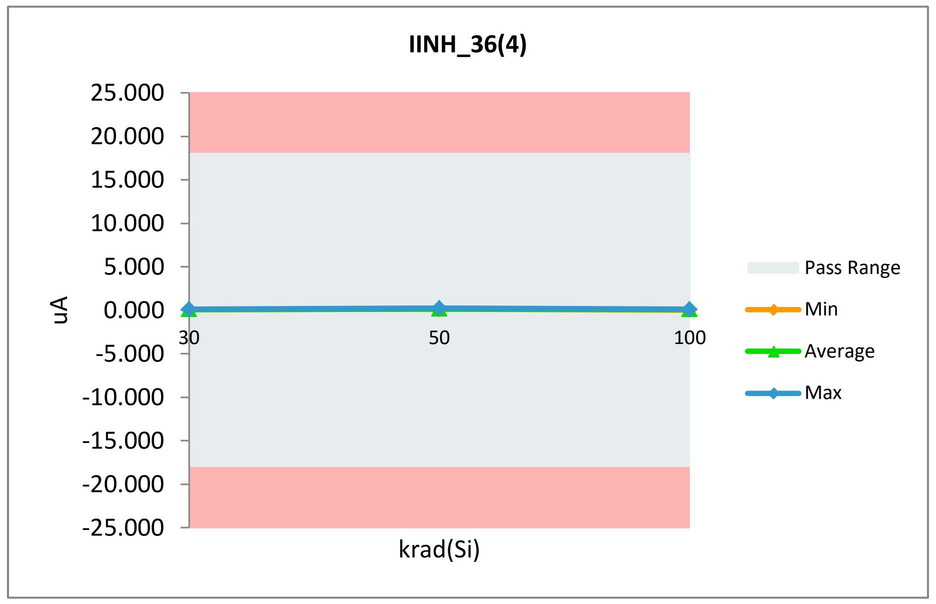


HDR TID Report T0 data
SN55LVCP22A-SP

		IINH_36(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	0.126	0.099	0.027
30	2	0.108	0.099	0.009
30	3	0.126	0.118	0.009
30	4	0.126	0.118	0.009
30	5	0.108	0.099	0.009
50	11	0.108	0.137	-0.029
50	12	0.126	0.118	0.009
50	13	0.145	0.118	0.027
50	14	0.126	0.248	-0.122
50	15	0.145	0.118	0.027
100	22	0.104	0.061	0.042
100	23	0.122	0.080	0.042
100	24	0.122	0.080	0.042
100	25	0.141	0.098	0.042
100	26	0.122	0.117	0.005
100	27	0.141	0.098	0.042
100	28	0.104	0.080	0.024
100	29	0.160	0.117	0.042
100	30	0.122	0.080	0.042
100	31	0.122	0.080	0.042
100	32	0.104	0.080	0.024
100	33	0.122	0.098	0.024
100	34	0.122	0.042	0.080
100	35	0.122	0.080	0.042
100	36	0.122	0.080	0.042
100	37	0.122	0.080	0.042
100	38	0.122	0.080	0.042
100	39	0.104	0.080	0.024
100	40	0.141	0.098	0.042
100	41	0.122	0.080	0.042
100	42	0.122	0.080	0.042
100	43	0.141	0.117	0.024
100	44	0.141	0.117	0.024
	Max	0.160	0.248	0.080
	Average	0.125	0.099	0.025
	Min	0.104	0.042	-0.122
	Std Dev	0.014	0.034	0.033

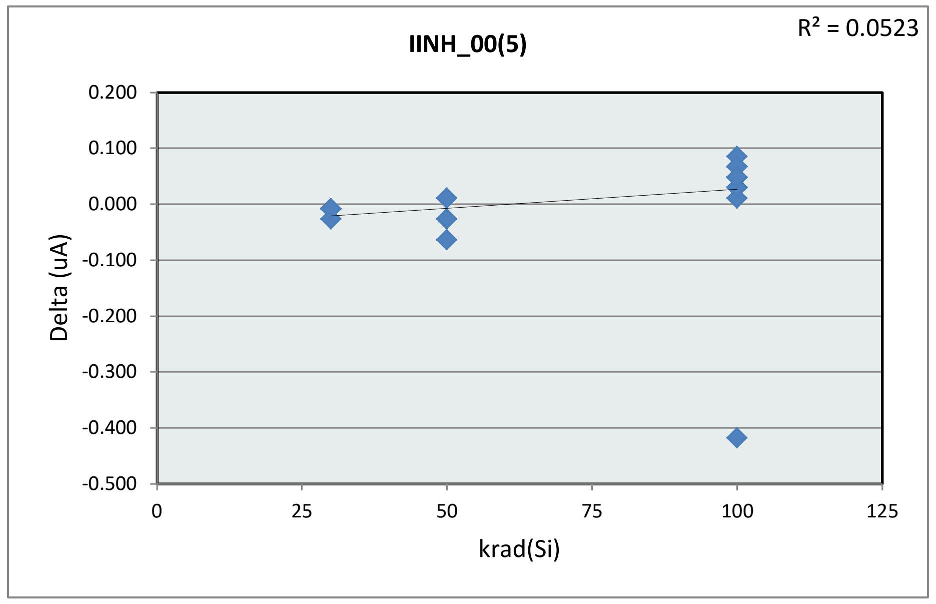


	IINH_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.099	0.118	0.042
Average	0.107	0.148	0.087
Max	0.118	0.248	0.117
UL	18.000	18.000	18.000

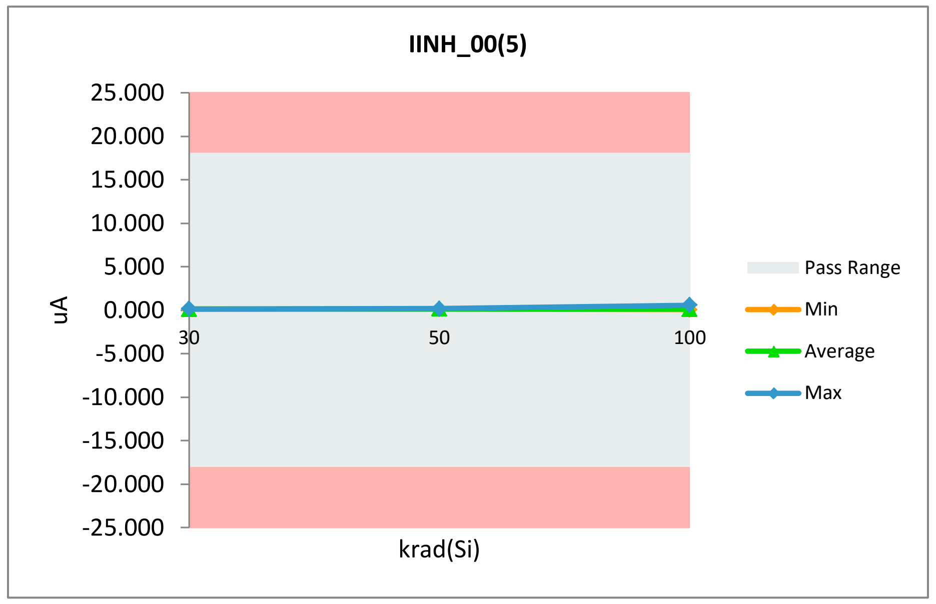


HDR TID Report T0 data
SN55LVCP22A-SP

		IINH_00(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.125	0.133	-0.008
30	2	0.106	0.114	-0.008
30	3	0.143	0.151	-0.008
30	4	0.125	0.151	-0.027
30	5	0.106	0.114	-0.008
50	11	0.106	0.170	-0.064
50	12	0.143	0.133	0.010
50	13	0.143	0.133	0.010
50	14	0.125	0.151	-0.027
50	15	0.125	0.151	-0.027
100	22	0.130	0.081	0.048
100	23	0.148	0.081	0.067
100	24	0.148	0.081	0.067
100	25	0.167	0.100	0.067
100	26	0.148	0.119	0.029
100	27	0.167	0.119	0.048
100	28	0.130	0.119	0.011
100	29	0.167	0.584	-0.418
100	30	0.148	0.100	0.048
100	31	0.167	0.100	0.067
100	32	0.130	0.100	0.029
100	33	0.148	0.119	0.029
100	34	0.148	0.063	0.085
100	35	0.148	0.081	0.067
100	36	0.148	0.100	0.048
100	37	0.130	0.100	0.029
100	38	0.130	0.063	0.067
100	39	0.148	0.100	0.048
100	40	0.130	0.100	0.029
100	41	0.148	0.119	0.029
100	42	0.148	0.100	0.048
100	43	0.167	0.119	0.048
100	44	0.167	0.119	0.048
	Max	0.167	0.584	0.085
	Average	0.141	0.126	0.015
	Min	0.106	0.063	-0.418
	Std Dev	0.018	0.086	0.085

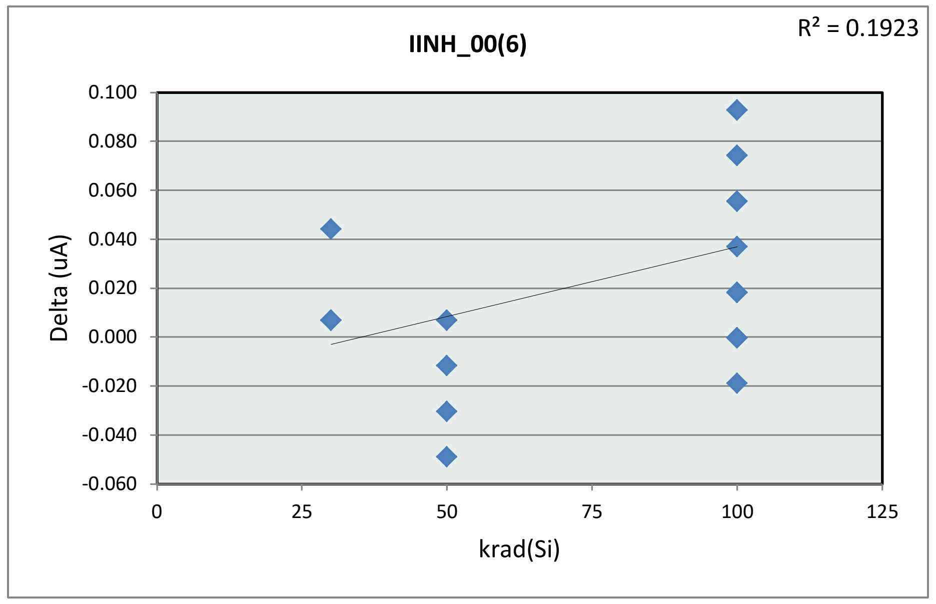


	IINH_00(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.114	0.133	0.063
Average	0.133	0.148	0.120
Max	0.151	0.170	0.584
UL	18.000	18.000	18.000

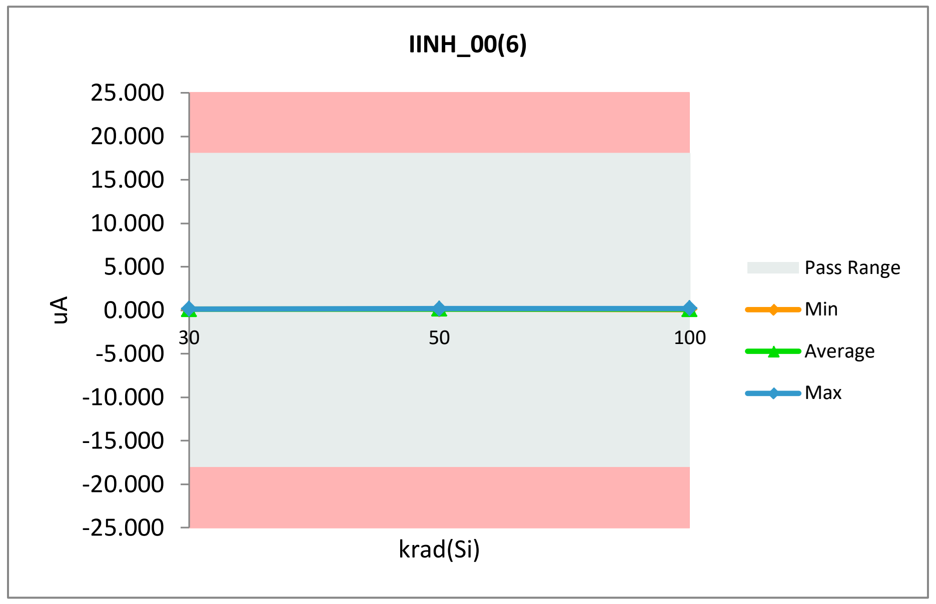


HDR TID Report T0 data
SN55LVCP22A-SP

		IINH_00(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	0.145	0.138	0.007
30	2	0.126	0.119	0.007
30	3	0.145	0.138	0.007
30	4	0.182	0.138	0.044
30	5	0.163	0.157	0.007
50	11	0.126	0.119	0.007
50	12	0.182	0.175	0.007
50	13	0.163	0.194	-0.030
50	14	0.126	0.138	-0.012
50	15	0.145	0.194	-0.049
100	22	0.100	0.101	0.000
100	23	0.138	0.138	0.000
100	24	0.193	0.101	0.093
100	25	0.156	0.138	0.018
100	26	0.193	0.212	-0.019
100	27	0.193	0.101	0.093
100	28	0.119	0.101	0.018
100	29	0.193	0.101	0.093
100	30	0.156	0.101	0.055
100	31	0.138	0.101	0.037
100	32	0.156	0.101	0.055
100	33	0.175	0.157	0.018
100	34	0.175	0.101	0.074
100	35	0.175	0.119	0.055
100	36	0.119	0.101	0.018
100	37	0.138	0.138	0.000
100	38	0.119	0.082	0.037
100	39	0.100	0.101	0.000
100	40	0.138	0.119	0.018
100	41	0.100	0.101	0.000
100	42	0.175	0.101	0.074
100	43	0.193	0.119	0.074
100	44	0.193	0.119	0.074
	Max	0.193	0.212	0.093
	Average	0.153	0.126	0.027
	Min	0.100	0.082	-0.049
	Std Dev	0.030	0.032	0.037

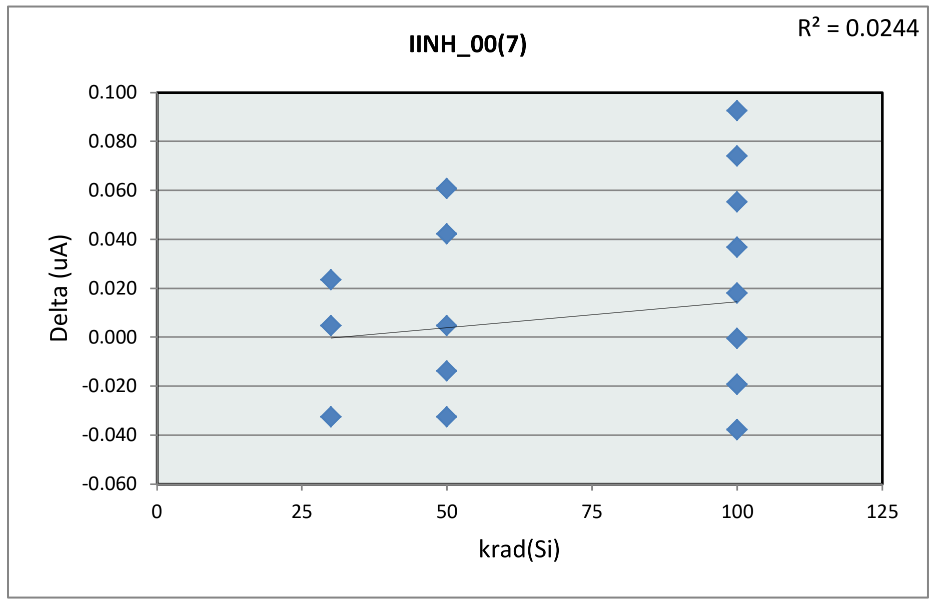


	IINH_00(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.119	0.119	0.082
Average	0.138	0.164	0.115
Max	0.157	0.194	0.212
UL	18.000	18.000	18.000

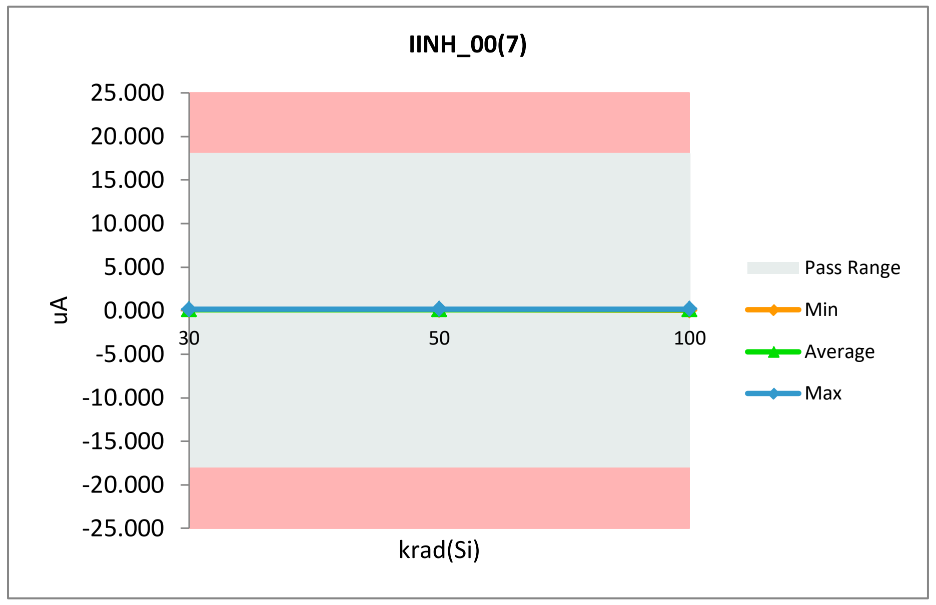


HDR TID Report T0 data
SN55LVCP22A-SP

		IINH_00(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	0.157	0.152	0.005
30	2	0.101	0.096	0.005
30	3	0.175	0.152	0.023
30	4	0.119	0.152	-0.033
30	5	0.082	0.115	-0.033
50	11	0.138	0.096	0.042
50	12	0.138	0.133	0.005
50	13	0.138	0.171	-0.033
50	14	0.138	0.152	-0.014
50	15	0.175	0.115	0.061
100	22	0.157	0.064	0.093
100	23	0.157	0.083	0.074
100	24	0.119	0.139	-0.019
100	25	0.157	0.139	0.018
100	26	0.157	0.194	-0.038
100	27	0.119	0.139	-0.019
100	28	0.157	0.083	0.074
100	29	0.157	0.157	-0.001
100	30	0.101	0.139	-0.038
100	31	0.119	0.139	-0.019
100	32	0.119	0.083	0.037
100	33	0.119	0.157	-0.038
100	34	0.119	0.045	0.074
100	35	0.119	0.064	0.055
100	36	0.175	0.120	0.055
100	37	0.119	0.139	-0.019
100	38	0.157	0.120	0.037
100	39	0.157	0.139	0.018
100	40	0.101	0.101	-0.001
100	41	0.101	0.120	-0.019
100	42	0.119	0.157	-0.038
100	43	0.119	0.101	0.018
100	44	0.119	0.101	0.018
	Max	0.175	0.194	0.093
	Average	0.133	0.123	0.011
	Min	0.082	0.045	-0.038
	Std Dev	0.025	0.034	0.039



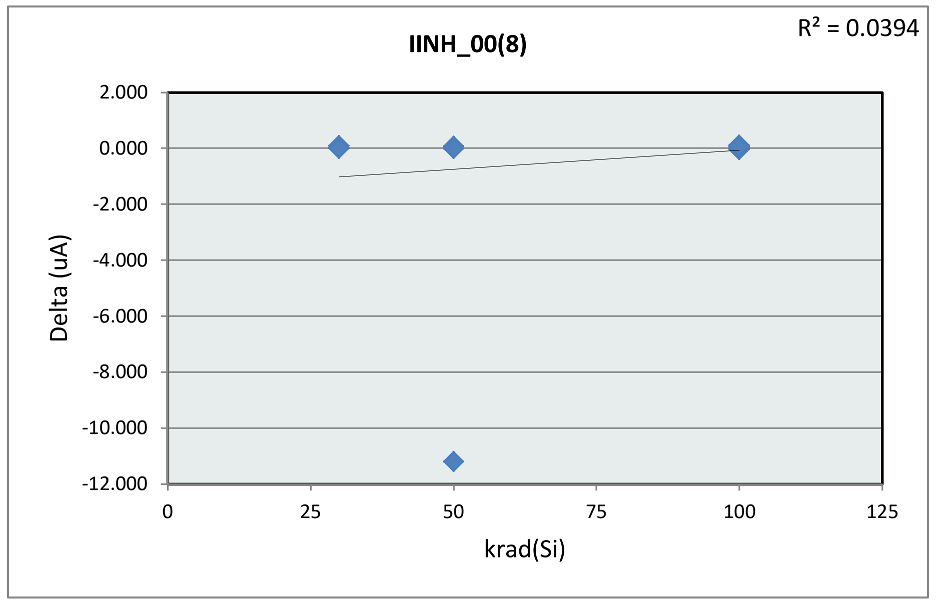
	IINH_00(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.096	0.096	0.045
Average	0.133	0.133	0.118
Max	0.152	0.171	0.194
UL	18.000	18.000	18.000



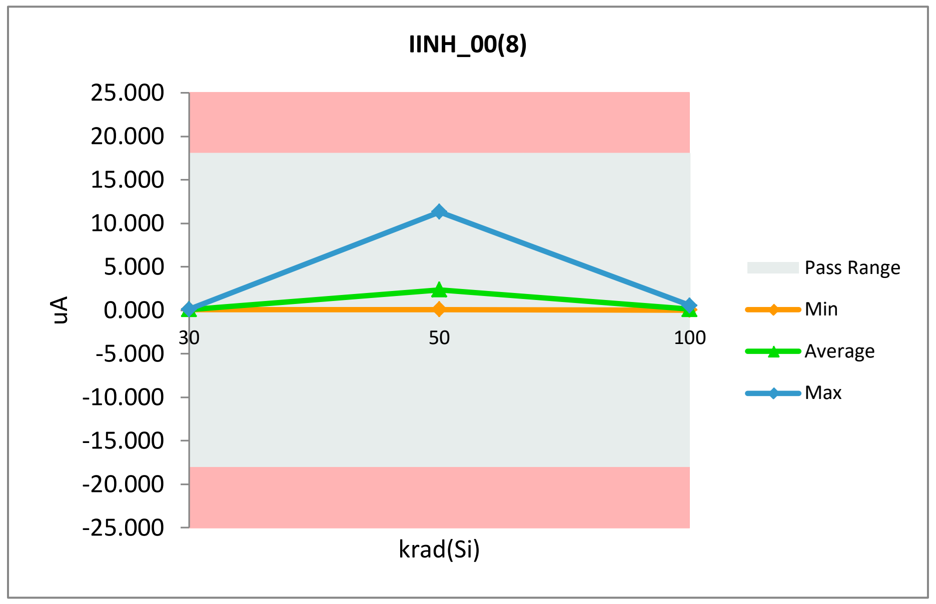
HDR TID Report T0 data
SN55LVCP22A-SP

	IINH_00(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.089	0.081	0.009
30	2	0.126	0.118	0.009
30	3	0.164	0.081	0.083
30	4	0.164	0.081	0.083
30	5	0.108	0.118	-0.010
50	11	0.145	0.081	0.064
50	12	0.145	0.155	-0.010
50	13	0.126	0.081	0.046
50	14	0.126	11.328	-11.202
50	15	0.108	0.118	-0.010
100	22	0.085	0.061	0.024
100	23	0.085	0.117	-0.032
100	24	0.160	0.117	0.042
100	25	0.160	0.061	0.098
100	26	0.085	0.098	-0.014
100	27	0.085	0.136	-0.051
100	28	0.141	0.117	0.024
100	29	0.626	0.546	0.079
100	30	0.122	0.117	0.005
100	31	0.066	0.117	-0.051
100	32	0.141	0.080	0.061
100	33	0.066	0.061	0.005
100	34	0.141	0.098	0.042
100	35	0.122	0.061	0.061
100	36	0.141	0.061	0.080
100	37	0.085	0.098	-0.014
100	38	0.085	0.080	0.005
100	39	0.066	0.098	-0.032
100	40	0.327	0.285	0.042
100	41	0.141	0.042	0.098
100	42	0.085	0.098	-0.014
100	43	0.160	0.117	0.042
100	44	0.160	0.117	0.042
	Max	0.626	11.328	0.098
	Average	0.140	0.455	-0.315
	Min	0.066	0.042	-11.202
	Std Dev	0.100	1.954	1.955



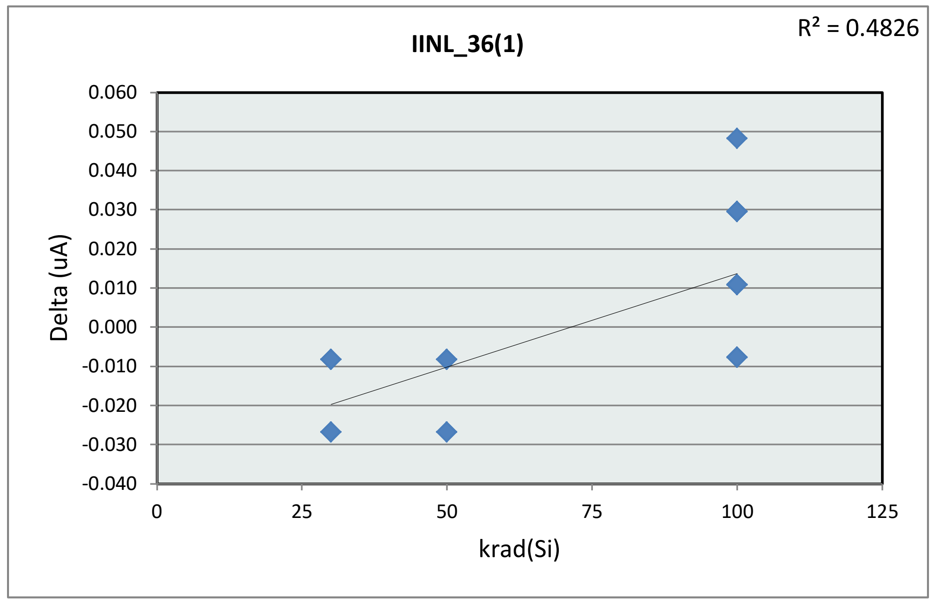
	IINH_00(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.081	0.081	0.042
Average	0.096	2.352	0.121
Max	0.118	11.328	0.546
UL	18.000	18.000	18.000



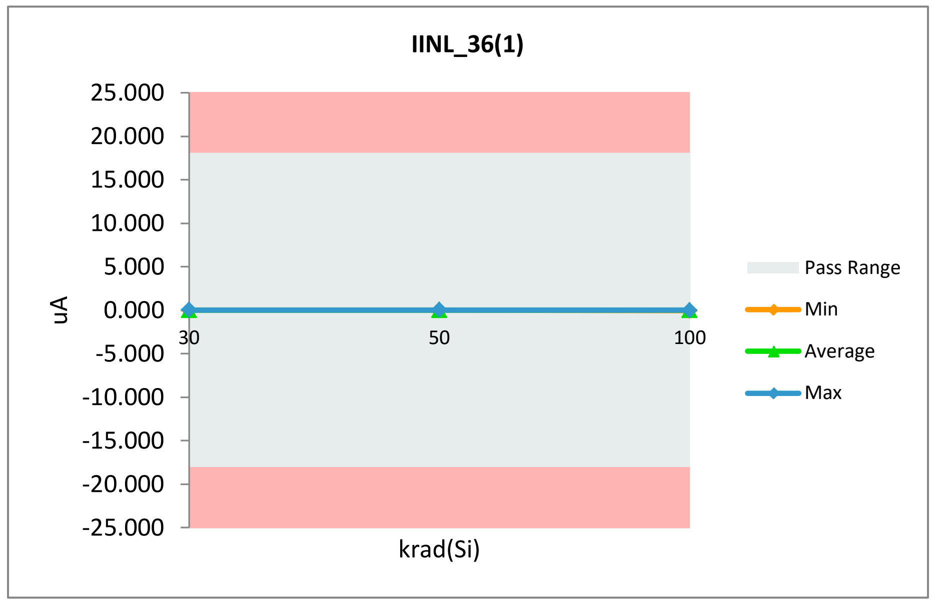
HDR TID Report T0 data
SN55LVCP22A-SP

	IINL_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.006	0.021	-0.027
30	2	-0.006	0.003	-0.008
30	3	-0.006	0.003	-0.008
30	4	-0.006	0.021	-0.027
30	5	0.013	0.021	-0.008
50	11	-0.006	0.003	-0.008
50	12	-0.006	0.003	-0.008
50	13	-0.006	0.021	-0.027
50	14	0.013	0.021	-0.008
50	15	-0.006	0.021	-0.027
100	22	-0.001	-0.012	0.011
100	23	-0.001	0.007	-0.008
100	24	-0.001	-0.012	0.011
100	25	0.018	-0.012	0.030
100	26	0.018	-0.012	0.030
100	27	0.018	-0.012	0.030
100	28	0.018	-0.012	0.030
100	29	-0.001	-0.049	0.048
100	30	0.018	-0.012	0.030
100	31	0.018	-0.012	0.030
100	32	0.018	0.007	0.011
100	33	-0.001	0.007	-0.008
100	34	0.018	0.007	0.011
100	35	-0.001	0.007	-0.008
100	36	0.018	-0.012	0.030
100	37	0.018	0.007	0.011
100	38	-0.001	0.007	-0.008
100	39	-0.001	-0.012	0.011
100	40	0.018	0.007	0.011
100	41	0.018	0.007	0.011
100	42	-0.001	0.007	-0.008
100	43	-0.001	-0.012	0.011
100	44	-0.001	-0.012	0.011
	Max	0.018	0.021	0.048
	Average	0.006	0.000	0.005
	Min	-0.006	-0.049	-0.027
	Std Dev	0.010	0.015	0.020

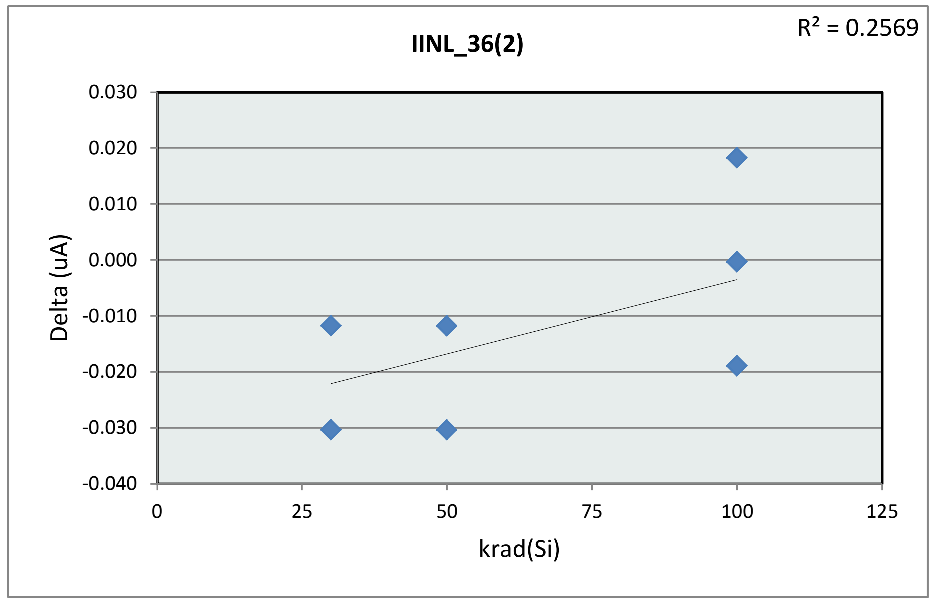


	IINL_36(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.003	0.003	-0.049
Average	0.014	0.014	-0.005
Max	0.021	0.021	0.007
UL	18.000	18.000	18.000

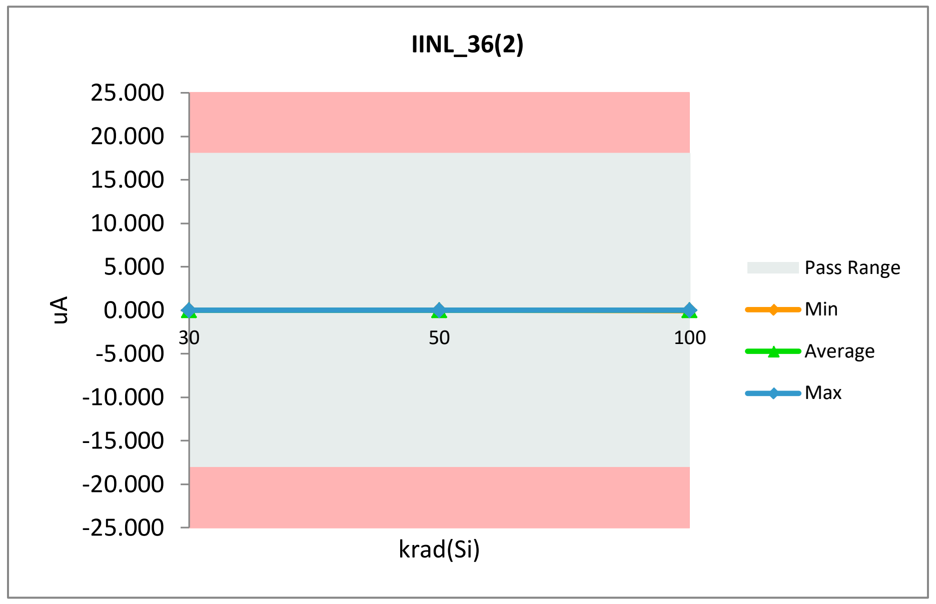


HDR TID Report T0 data
SN55LVCP22A-SP

		IINL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	-0.023	-0.011	-0.012
30	2	-0.023	0.008	-0.030
30	3	-0.023	-0.011	-0.012
30	4	-0.023	0.008	-0.030
30	5	-0.023	0.008	-0.030
50	11	-0.004	0.008	-0.012
50	12	-0.023	0.008	-0.030
50	13	-0.004	0.008	-0.012
50	14	-0.004	0.008	-0.012
50	15	-0.004	0.008	-0.012
100	22	-0.011	0.008	-0.019
100	23	-0.011	0.008	-0.019
100	24	-0.011	-0.011	0.000
100	25	-0.011	0.008	-0.019
100	26	-0.011	-0.030	0.018
100	27	-0.011	0.008	-0.019
100	28	-0.011	-0.011	0.000
100	29	-0.011	-0.011	0.000
100	30	-0.011	-0.011	0.000
100	31	0.007	-0.011	0.018
100	32	-0.011	0.008	-0.019
100	33	-0.011	-0.011	0.000
100	34	-0.011	0.008	-0.019
100	35	-0.011	-0.011	0.000
100	36	-0.011	0.008	-0.019
100	37	0.007	0.008	0.000
100	38	0.007	-0.011	0.018
100	39	0.007	-0.011	0.018
100	40	-0.011	-0.011	0.000
100	41	-0.011	-0.011	0.000
100	42	0.007	-0.011	0.018
100	43	-0.011	0.008	-0.019
100	44	-0.011	0.008	-0.019
	Max	0.007	0.008	0.018
	Average	-0.010	-0.001	-0.008
	Min	-0.023	-0.030	-0.030
	Std Dev	0.009	0.011	0.015

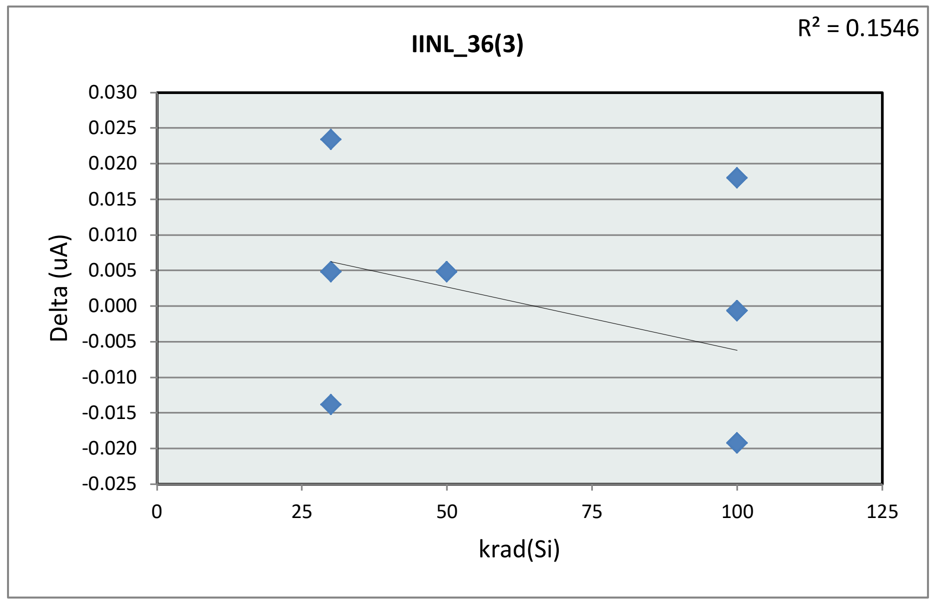


	IINL_36(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	-0.011	0.008	-0.030
Average	0.000	0.008	-0.004
Max	0.008	0.008	0.008
UL	18.000	18.000	18.000

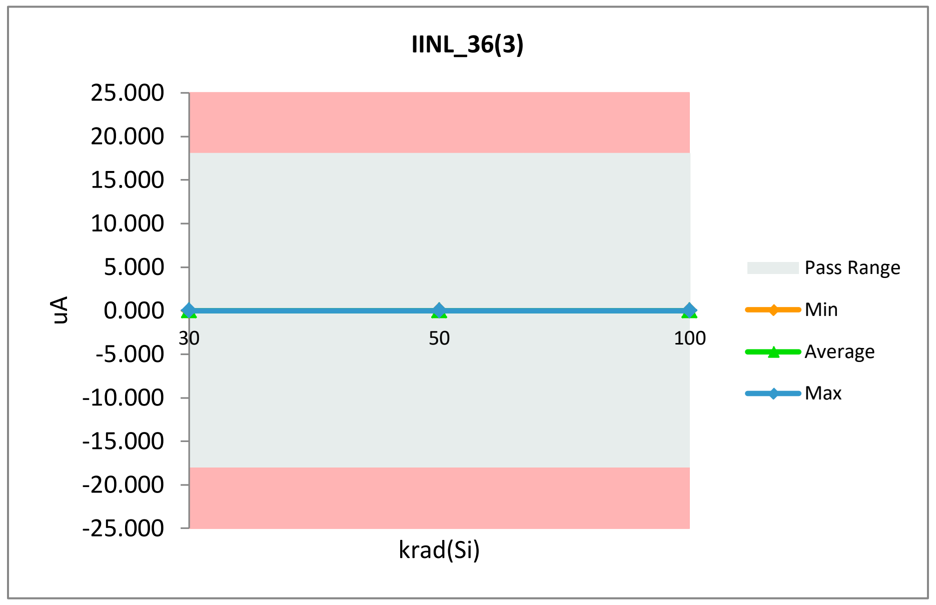


HDR TID Report T0 data
SN55LVCP22A-SP

		IINL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	0.008	0.003	0.005
30	2	0.008	0.003	0.005
30	3	0.008	0.003	0.005
30	4	-0.011	0.003	-0.014
30	5	0.008	-0.016	0.023
50	11	0.008	0.003	0.005
50	12	0.008	0.003	0.005
50	13	0.008	0.003	0.005
50	14	0.008	0.003	0.005
50	15	0.008	0.003	0.005
100	22	-0.011	0.008	-0.019
100	23	-0.011	0.008	-0.019
100	24	-0.011	0.008	-0.019
100	25	-0.011	0.008	-0.019
100	26	-0.011	-0.011	-0.001
100	27	-0.011	0.008	-0.019
100	28	-0.011	0.008	-0.019
100	29	0.007	0.008	-0.001
100	30	0.007	0.008	-0.001
100	31	-0.011	0.008	-0.019
100	32	0.007	0.008	-0.001
100	33	0.007	0.008	-0.001
100	34	-0.011	-0.011	-0.001
100	35	0.007	0.008	-0.001
100	36	-0.011	0.008	-0.019
100	37	-0.011	-0.011	-0.001
100	38	0.007	0.008	-0.001
100	39	0.007	-0.011	0.018
100	40	-0.011	0.008	-0.019
100	41	-0.011	0.008	-0.019
100	42	0.007	0.008	-0.001
100	43	0.007	-0.011	0.018
100	44	0.007	-0.011	0.018
	Max	0.008	0.008	0.023
	Average	0.000	0.003	-0.003
	Min	-0.011	-0.016	-0.019
	Std Dev	0.009	0.008	0.013



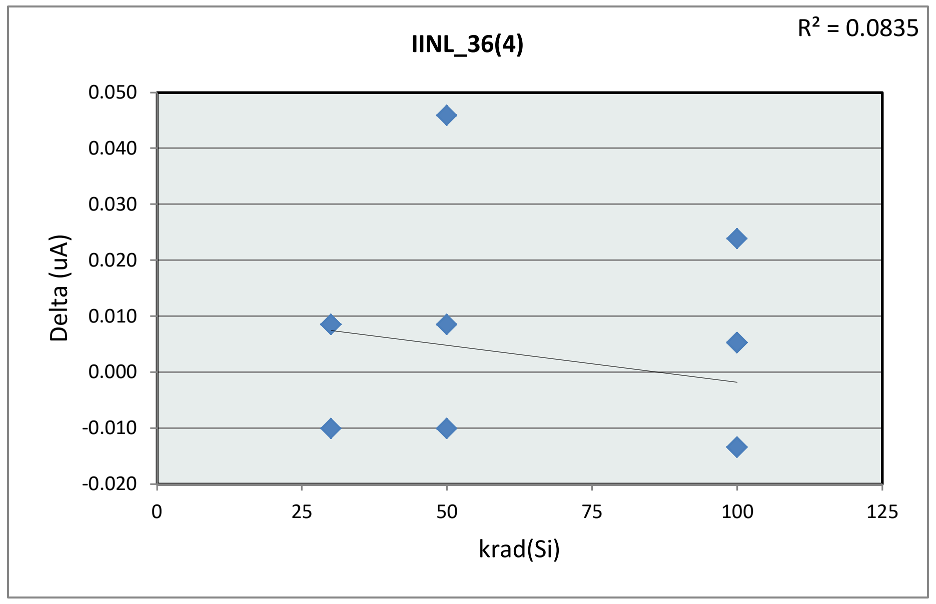
	IINL_36(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	-0.016	0.003	-0.011
Average	-0.001	0.003	0.003
Max	0.003	0.003	0.008
UL	18.000	18.000	18.000



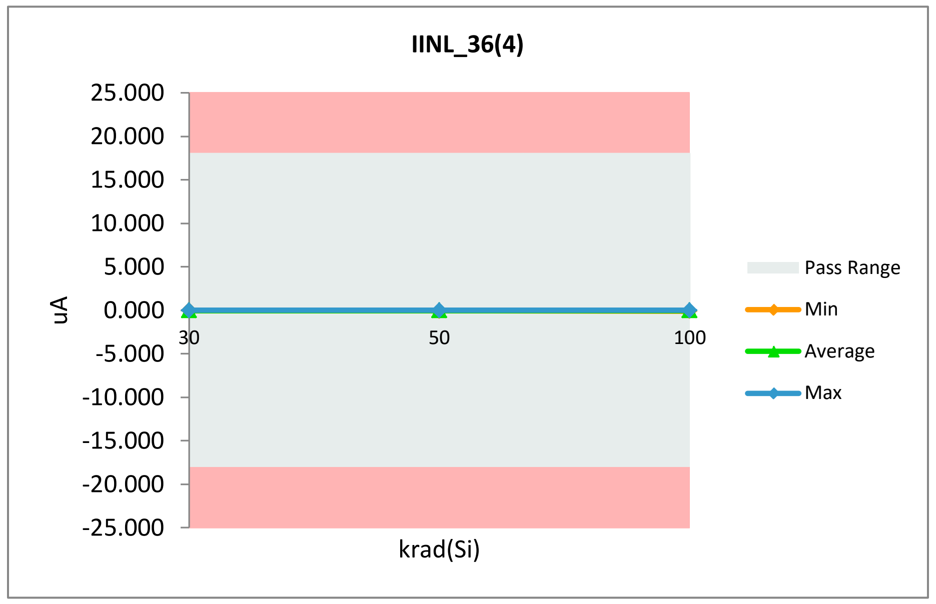
HDR TID Report T0 data
SN55LVCP22A-SP

	IINL_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-0.023	-0.031	0.009
30	2	-0.023	-0.031	0.009
30	3	-0.023	-0.031	0.009
30	4	-0.023	-0.031	0.009
30	5	-0.023	-0.013	-0.010
50	11	-0.023	-0.013	-0.010
50	12	-0.023	-0.013	-0.010
50	13	-0.023	-0.031	0.009
50	14	-0.023	-0.069	0.046
50	15	-0.023	-0.031	0.009
100	22	-0.027	-0.032	0.005
100	23	-0.027	-0.032	0.005
100	24	-0.027	-0.032	0.005
100	25	-0.027	-0.032	0.005
100	26	-0.027	-0.032	0.005
100	27	-0.027	-0.014	-0.013
100	28	-0.027	-0.014	-0.013
100	29	-0.083	-0.088	0.005
100	30	-0.027	-0.014	-0.013
100	31	-0.027	-0.032	0.005
100	32	-0.027	-0.014	-0.013
100	33	-0.027	-0.032	0.005
100	34	-0.027	-0.032	0.005
100	35	-0.027	-0.014	-0.013
100	36	-0.027	-0.032	0.005
100	37	-0.027	-0.014	-0.013
100	38	-0.027	-0.032	0.005
100	39	-0.027	-0.032	0.005
100	40	-0.027	-0.051	0.024
100	41	-0.027	-0.014	-0.013
100	42	-0.027	-0.014	-0.013
100	43	-0.027	-0.014	-0.013
100	44	-0.027	-0.014	-0.013
	Max	-0.023	-0.013	0.046
	Average	-0.027	-0.028	0.001
	Min	-0.083	-0.088	-0.013
	Std Dev	0.010	0.017	0.013

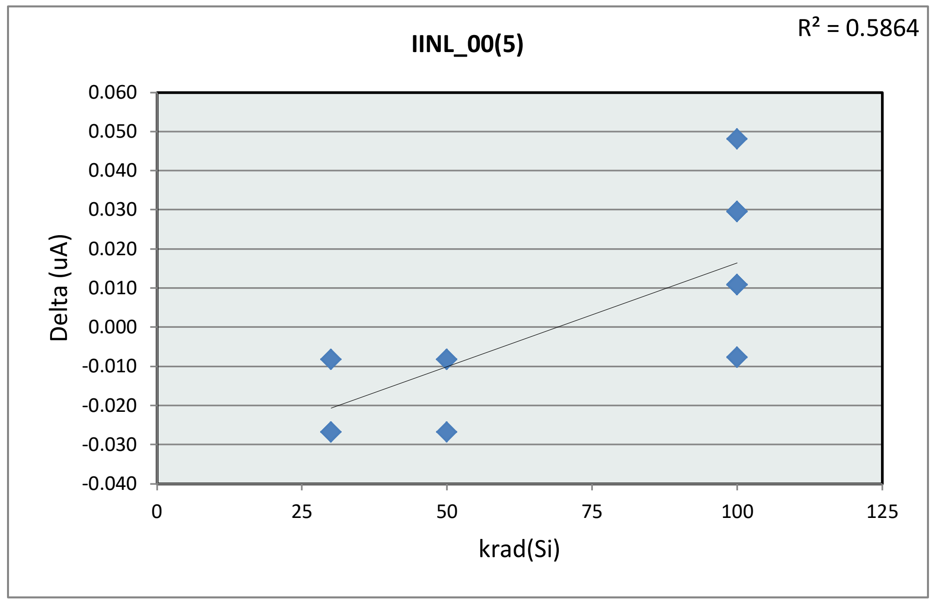


	IINL_36(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	-0.031	-0.069	-0.088
Average	-0.028	-0.031	-0.027
Max	-0.013	-0.013	-0.014
UL	18.000	18.000	18.000

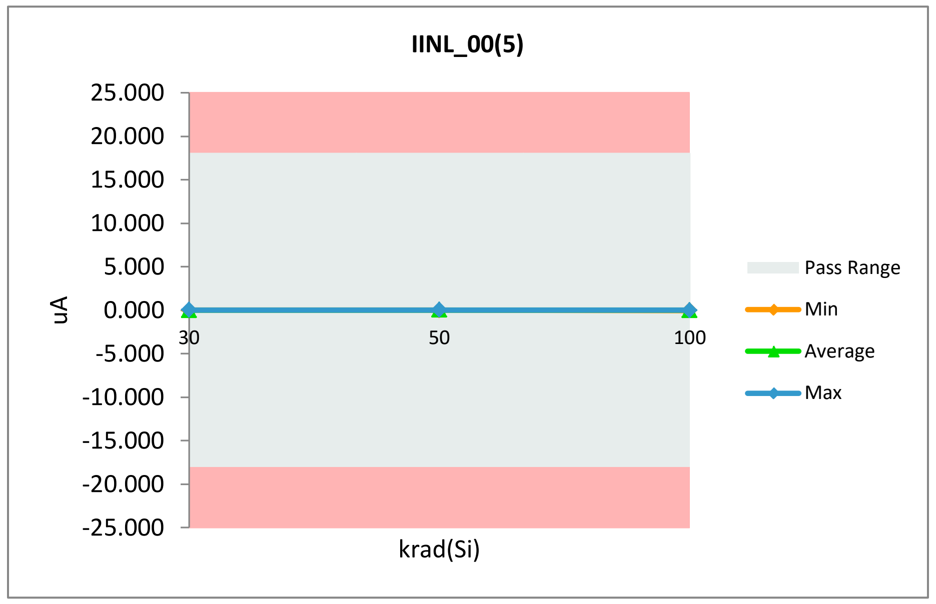


HDR TID Report T0 data
SN55LVCP22A-SP

		IINL_00(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-0.006	0.003	-0.008
30	2	-0.006	0.021	-0.027
30	3	-0.006	0.021	-0.027
30	4	-0.006	0.021	-0.027
30	5	-0.006	0.003	-0.008
50	11	-0.006	0.003	-0.008
50	12	0.013	0.021	-0.008
50	13	0.013	0.021	-0.008
50	14	-0.006	0.021	-0.027
50	15	0.013	0.021	-0.008
100	22	0.018	-0.012	0.030
100	23	0.018	-0.012	0.030
100	24	0.018	0.007	0.011
100	25	0.018	-0.012	0.030
100	26	-0.001	-0.012	0.011
100	27	-0.001	0.007	-0.008
100	28	0.018	0.007	0.011
100	29	0.018	-0.030	0.048
100	30	-0.001	0.007	-0.008
100	31	0.018	0.007	0.011
100	32	-0.001	-0.012	0.011
100	33	0.018	-0.012	0.030
100	34	-0.001	-0.012	0.011
100	35	0.018	0.007	0.011
100	36	-0.001	0.007	-0.008
100	37	-0.001	-0.012	0.011
100	38	0.018	-0.012	0.030
100	39	0.018	-0.012	0.030
100	40	-0.001	-0.012	0.011
100	41	-0.001	-0.012	0.011
100	42	0.018	0.007	0.011
100	43	0.018	-0.012	0.030
100	44	0.018	-0.012	0.030
	Max	0.018	0.021	0.048
	Average	0.007	0.000	0.007
	Min	-0.006	-0.030	-0.027
	Std Dev	0.010	0.014	0.020

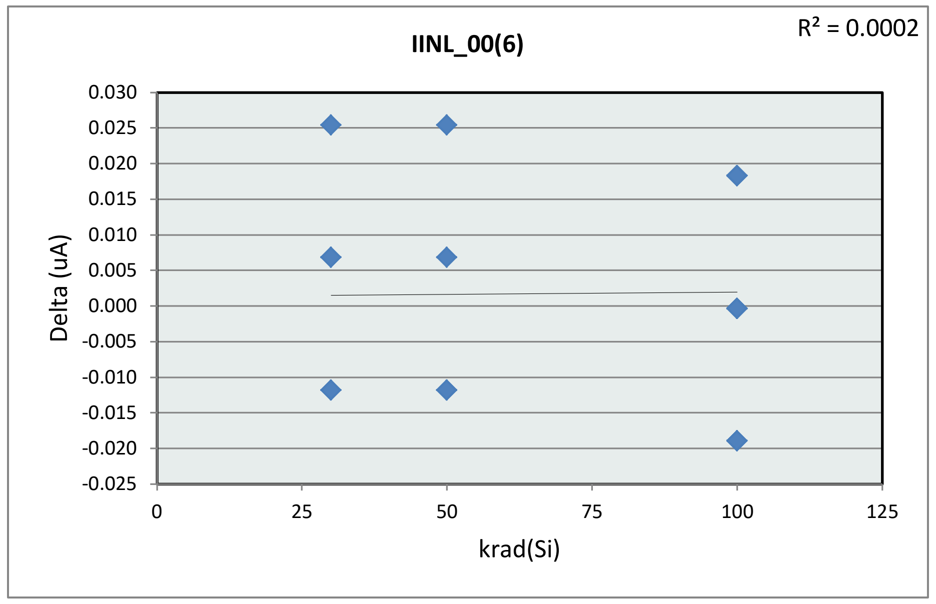


	IINL_00(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	0.003	0.003	-0.030
Average	0.014	0.017	-0.006
Max	0.021	0.021	0.007
UL	18.000	18.000	18.000

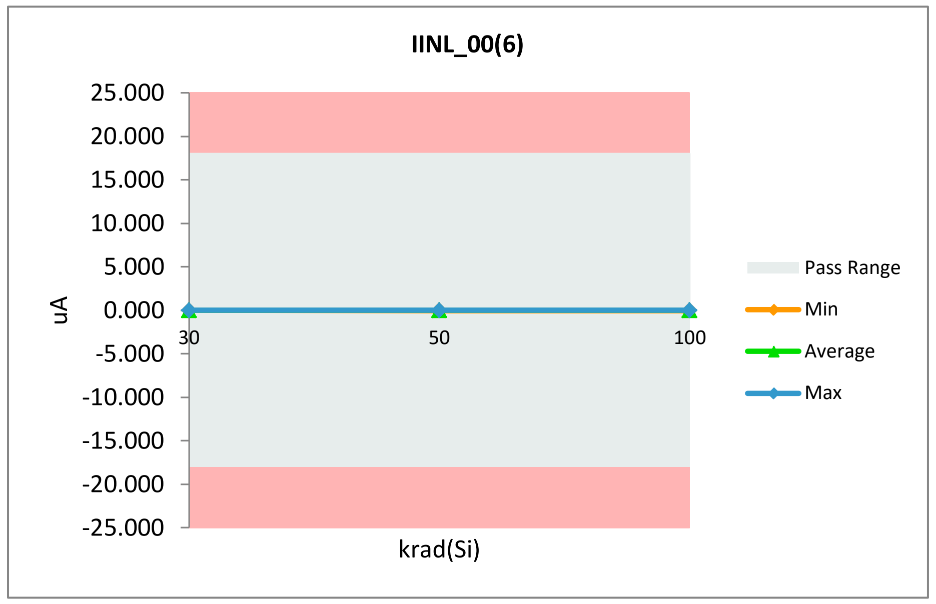


HDR TID Report T0 data
SN55LVCP22A-SP

		IINL_00(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.023	-0.011	-0.012
30	2	-0.004	-0.011	0.007
30	3	-0.004	-0.011	0.007
30	4	-0.004	0.008	-0.012
30	5	0.014	-0.011	0.025
50	11	-0.004	0.008	-0.012
50	12	-0.004	-0.011	0.007
50	13	-0.004	0.008	-0.012
50	14	-0.004	0.008	-0.012
50	15	-0.004	-0.030	0.025
100	22	0.007	0.008	0.000
100	23	0.007	-0.011	0.018
100	24	0.007	-0.011	0.018
100	25	-0.030	-0.011	-0.019
100	26	0.007	-0.011	0.018
100	27	-0.011	-0.011	0.000
100	28	0.007	0.008	0.000
100	29	0.007	-0.011	0.018
100	30	-0.011	-0.011	0.000
100	31	-0.011	-0.011	0.000
100	32	-0.011	0.008	-0.019
100	33	-0.011	-0.011	0.000
100	34	-0.011	0.008	-0.019
100	35	-0.011	0.008	-0.019
100	36	0.007	-0.011	0.018
100	37	0.007	0.008	0.000
100	38	0.007	-0.011	0.018
100	39	0.007	-0.011	0.018
100	40	-0.011	-0.030	0.018
100	41	-0.011	-0.011	0.000
100	42	-0.011	0.008	-0.019
100	43	-0.011	-0.011	0.000
100	44	-0.011	-0.011	0.000
	Max	0.014	0.008	0.025
	Average	-0.004	-0.006	0.002
	Min	-0.030	-0.030	-0.019
	Std Dev	0.010	0.011	0.014

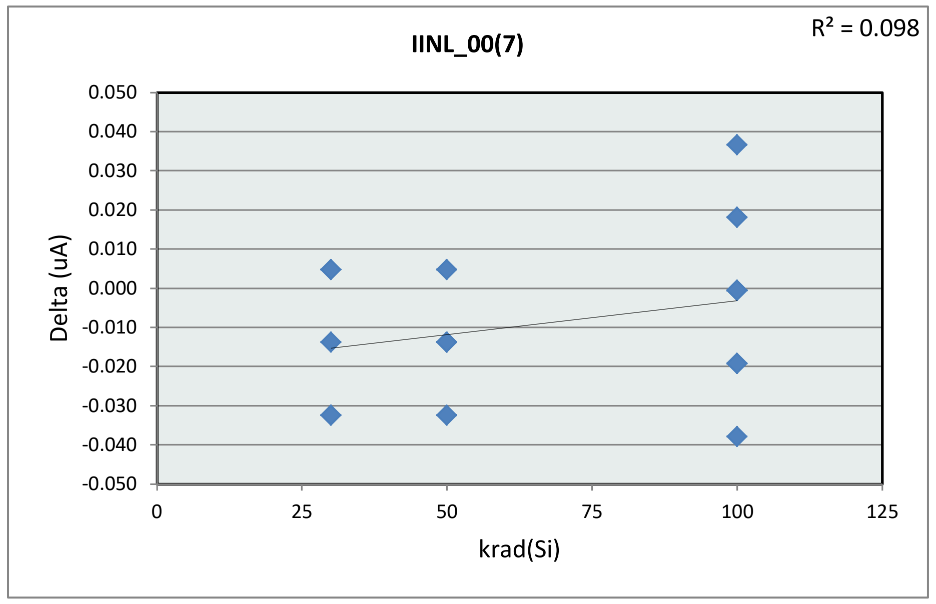


	IINL_00(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	-0.011	-0.030	-0.030
Average	-0.007	-0.003	-0.006
Max	0.008	0.008	0.008
UL	18.000	18.000	18.000

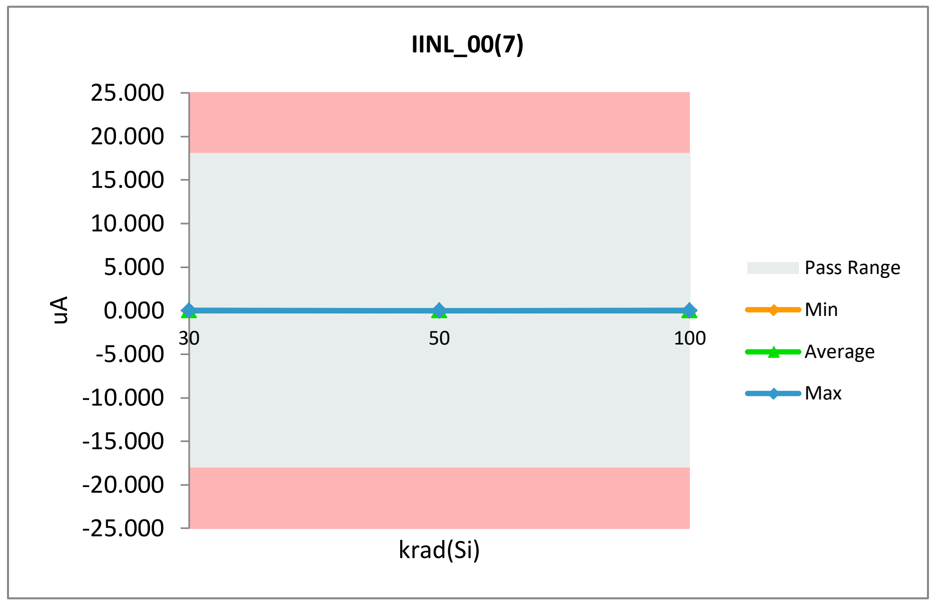


HDR TID Report T0 data
SN55LVCP22A-SP

		IINL_00(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.011	0.021	-0.033
30	2	-0.011	0.021	-0.033
30	3	-0.011	-0.016	0.005
30	4	-0.011	0.003	-0.014
30	5	0.008	0.003	0.005
50	11	-0.011	0.003	-0.014
50	12	-0.011	0.003	-0.014
50	13	-0.030	0.003	-0.033
50	14	-0.011	0.003	-0.014
50	15	-0.011	-0.016	0.005
100	22	-0.011	-0.011	-0.001
100	23	0.007	0.008	-0.001
100	24	0.007	0.008	-0.001
100	25	0.007	0.008	-0.001
100	26	-0.011	0.008	-0.019
100	27	-0.011	-0.011	-0.001
100	28	0.007	0.027	-0.019
100	29	0.007	0.008	-0.001
100	30	0.007	0.008	-0.001
100	31	0.007	0.008	-0.001
100	32	0.007	0.027	-0.019
100	33	-0.011	0.008	-0.019
100	34	0.007	-0.029	0.037
100	35	-0.030	0.008	-0.038
100	36	0.007	-0.011	0.018
100	37	-0.011	-0.011	-0.001
100	38	0.007	0.008	-0.001
100	39	-0.011	-0.011	-0.001
100	40	-0.011	0.008	-0.019
100	41	-0.011	-0.011	-0.001
100	42	0.007	-0.011	0.018
100	43	-0.011	-0.011	-0.001
100	44	-0.011	-0.011	-0.001
	Max	0.008	0.027	0.037
	Average	-0.005	0.001	-0.006
	Min	-0.030	-0.029	-0.038
	Std Dev	0.011	0.013	0.016

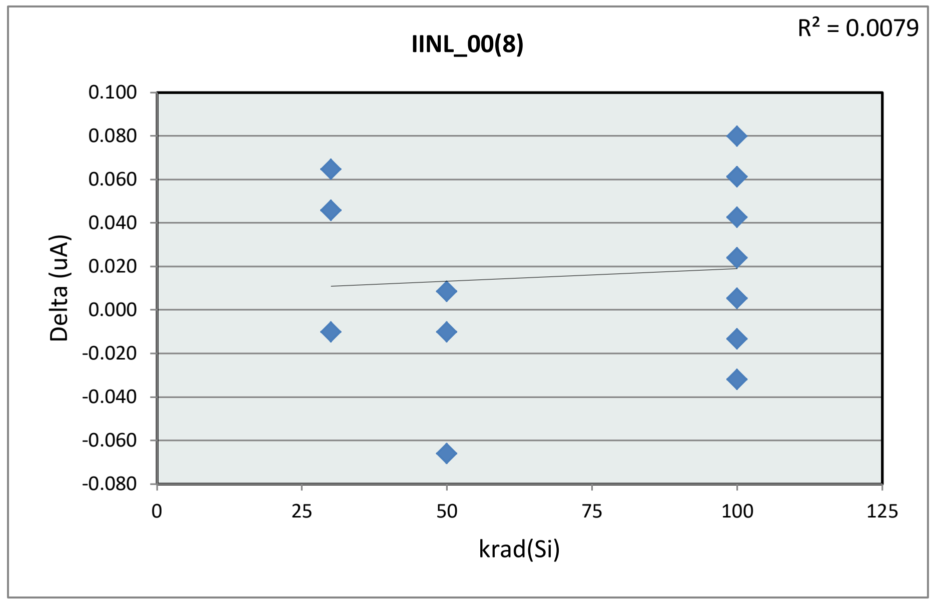


	IINL_00(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	-0.016	-0.016	-0.029
Average	0.006	-0.001	0.001
Max	0.021	0.003	0.027
UL	18.000	18.000	18.000

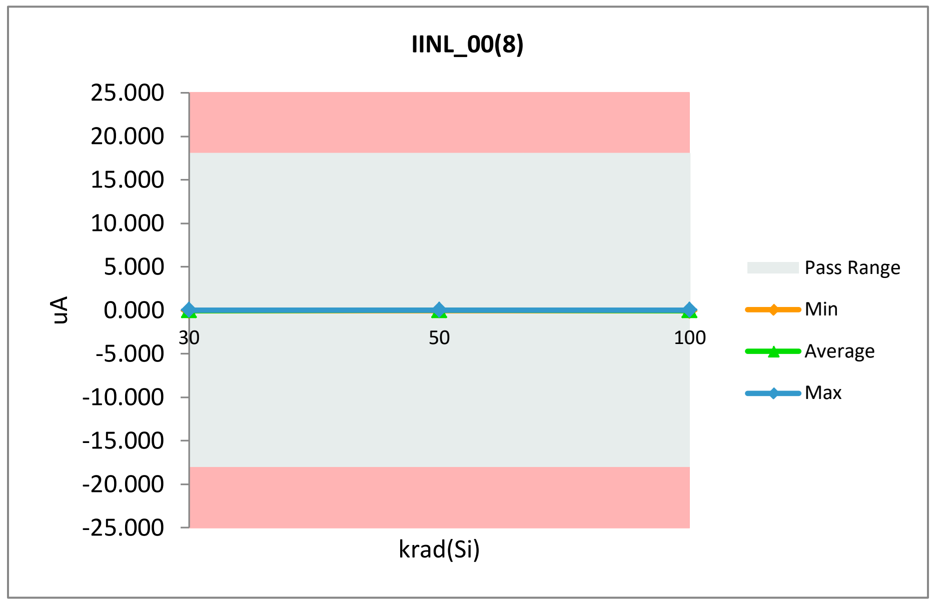


HDR TID Report T0 data
SN55LVCP22A-SP

		IINL_00(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.014	0.025	-0.010
30	2	0.014	-0.031	0.046
30	3	0.014	-0.050	0.064
30	4	0.014	-0.031	0.046
30	5	0.014	-0.031	0.046
50	11	-0.041	0.025	-0.066
50	12	-0.041	0.025	-0.066
50	13	0.014	0.006	0.009
50	14	-0.004	-0.013	0.009
50	15	-0.041	-0.031	-0.010
100	22	-0.027	-0.032	0.005
100	23	-0.027	-0.032	0.005
100	24	-0.027	-0.032	0.005
100	25	0.029	-0.032	0.061
100	26	-0.027	-0.032	0.005
100	27	0.010	0.024	-0.013
100	28	-0.008	-0.014	0.005
100	29	-0.008	-0.032	0.024
100	30	0.029	-0.032	0.061
100	31	-0.027	-0.051	0.024
100	32	0.010	-0.032	0.043
100	33	0.029	-0.032	0.061
100	34	0.029	-0.032	0.061
100	35	0.029	-0.032	0.061
100	36	-0.008	0.024	-0.032
100	37	-0.027	-0.032	0.005
100	38	-0.008	-0.051	0.043
100	39	-0.046	-0.014	-0.032
100	40	0.029	-0.051	0.080
100	41	-0.008	-0.032	0.024
100	42	-0.008	-0.032	0.024
100	43	-0.027	-0.014	-0.013
100	44	-0.027	-0.014	-0.013
	Max	0.029	0.025	0.080
	Average	-0.005	-0.022	0.017
	Min	-0.046	-0.051	-0.066
	Std Dev	0.025	0.023	0.037

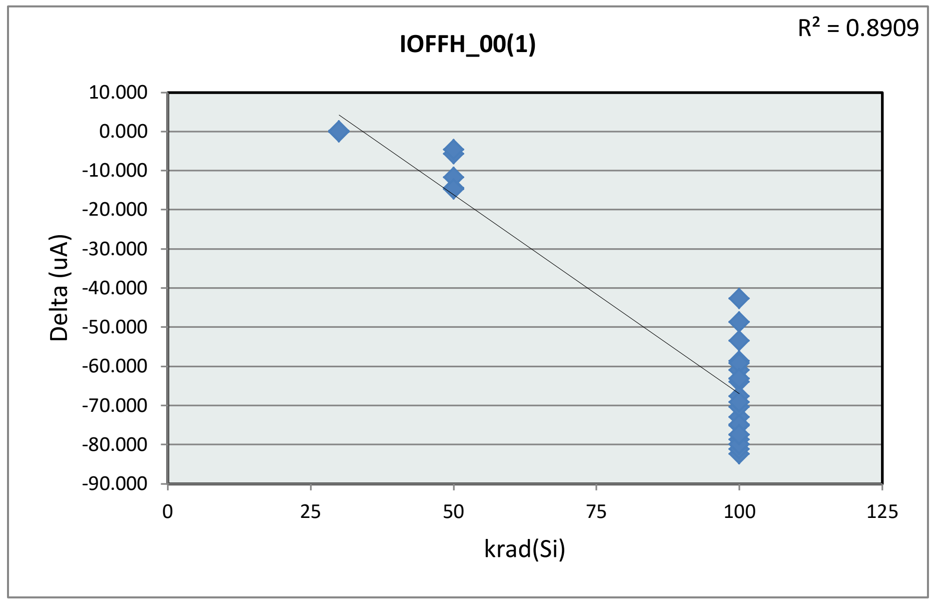


	IINL_00(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	18	uA	
Min Limit	-18	uA	
krad(Si)	30	50	100
LL	-18.000	-18.000	-18.000
Min	-0.050	-0.031	-0.051
Average	-0.024	0.002	-0.026
Max	0.025	0.025	0.024
UL	18.000	18.000	18.000

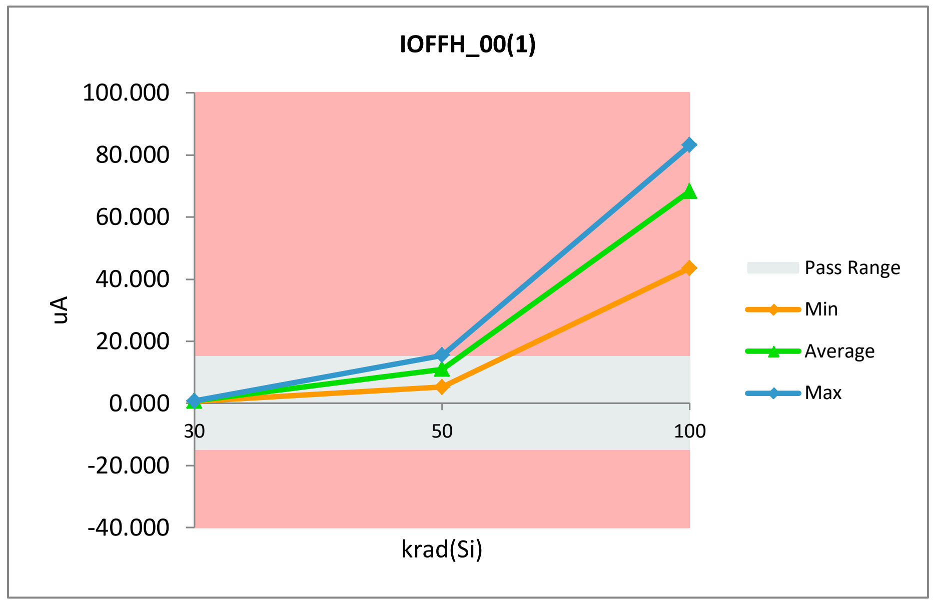


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFH_00(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.747	0.756	-0.008
30	2	0.766	0.718	0.048
30	3	0.692	0.849	-0.157
30	4	0.785	0.830	-0.045
30	5	0.766	0.830	-0.064
50	11	0.692	15.236	-14.544
50	12	0.803	12.531	-11.728
50	13	0.803	6.522	-5.719
50	14	0.617	5.320	-4.703
50	15	0.747	15.536	-14.789
100	22	0.845	49.571	-48.726
100	23	0.845	63.972	-63.127
100	24	0.545	59.172	-58.627
100	25	0.545	73.573	-73.028
100	26	0.845	79.574	-78.729
100	27	0.845	83.174	-82.329
100	28	0.845	81.974	-81.129
100	29	1.146	65.172	-64.026
100	30	0.845	71.173	-70.328
100	31	0.845	80.774	-79.929
100	32	1.146	68.773	-67.627
100	33	0.845	80.774	-79.929
100	34	0.845	43.570	-42.725
100	35	0.845	49.571	-48.726
100	36	0.545	61.572	-61.027
100	37	1.146	60.372	-59.226
100	38	0.845	54.371	-53.526
100	39	0.845	69.973	-69.128
100	40	0.845	75.973	-75.128
100	41	0.845	63.972	-63.127
100	42	1.146	75.973	-74.827
100	43	0.845	78.374	-77.529
100	44	0.845	78.374	-77.529
	Max	1.146	83.174	0.048
	Average	0.823	49.361	-48.538
	Min	0.545	0.718	-82.329
	Std Dev	0.154	30.818	30.765

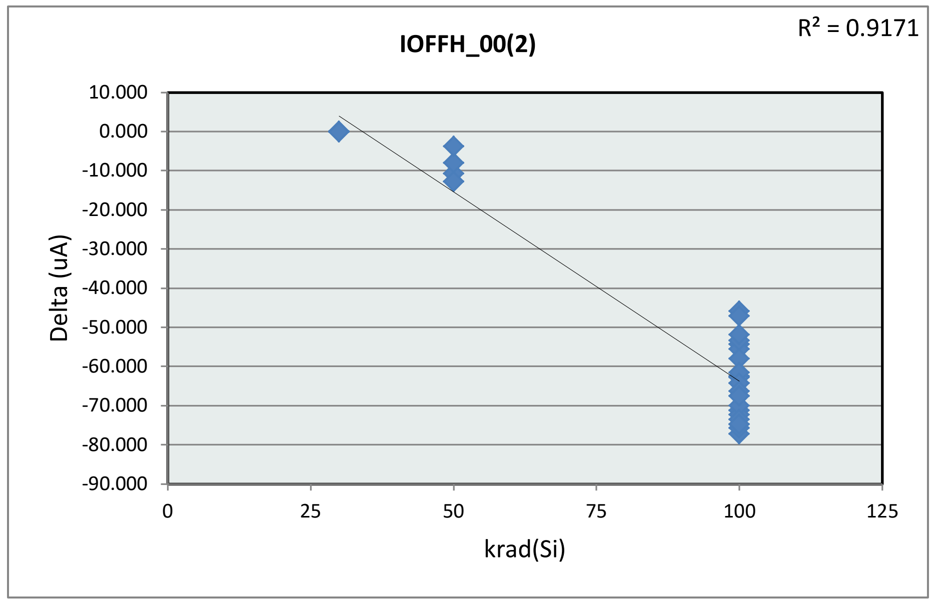


	IOFFH_00(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.718	5.320	43.570
Average	0.796	11.029	68.251
Max	0.849	15.536	83.174
UL	15.000	15.000	15.000

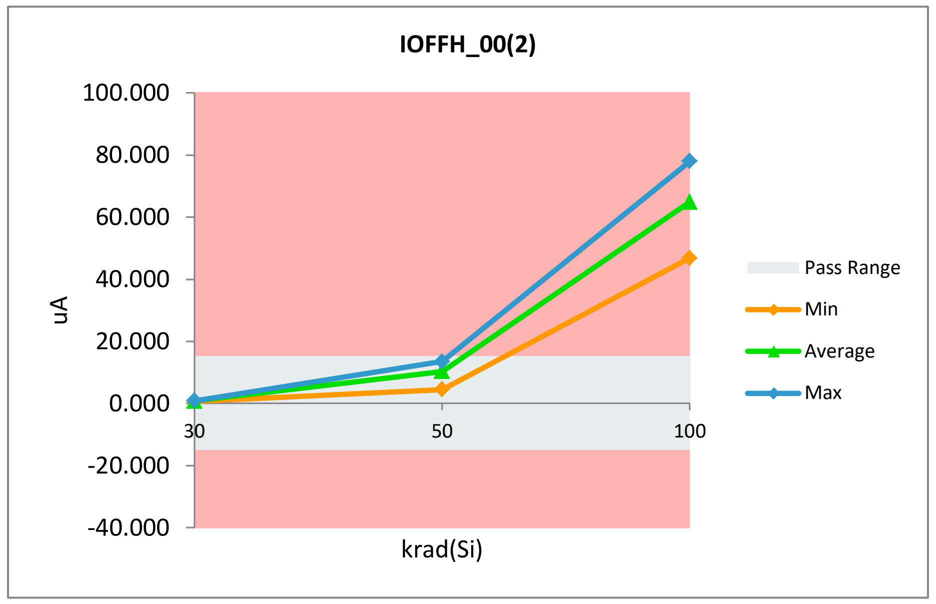


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFH_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	0.814	0.840	-0.027
30	2	0.702	0.766	-0.064
30	3	0.776	0.933	-0.157
30	4	0.795	0.803	-0.008
30	5	0.720	0.896	-0.175
50	11	0.720	13.560	-12.840
50	12	0.665	11.456	-10.791
50	13	0.739	8.750	-8.011
50	14	0.739	4.541	-3.802
50	15	0.683	13.560	-12.877
100	22	0.835	55.196	-54.361
100	23	0.835	56.397	-55.562
100	24	0.835	58.799	-57.964
100	25	0.835	75.612	-74.777
100	26	0.835	72.009	-71.174
100	27	0.835	78.014	-77.179
100	28	0.835	73.210	-72.375
100	29	1.135	63.603	-62.468
100	30	0.835	70.809	-69.974
100	31	1.135	76.813	-75.678
100	32	0.835	63.603	-62.768
100	33	0.835	74.411	-73.576
100	34	0.835	46.790	-45.955
100	35	0.835	47.991	-47.156
100	36	0.534	64.804	-64.270
100	37	0.534	53.995	-53.461
100	38	0.835	52.794	-51.959
100	39	0.835	62.402	-61.567
100	40	0.835	75.612	-74.777
100	41	0.534	64.804	-64.270
100	42	0.835	67.206	-66.371
100	43	0.835	68.407	-67.572
100	44	0.835	68.407	-67.572
	Max	1.135	78.014	-0.008
	Average	0.796	46.903	-46.107
	Min	0.534	0.766	-77.179
	Std Dev	0.127	28.864	28.820



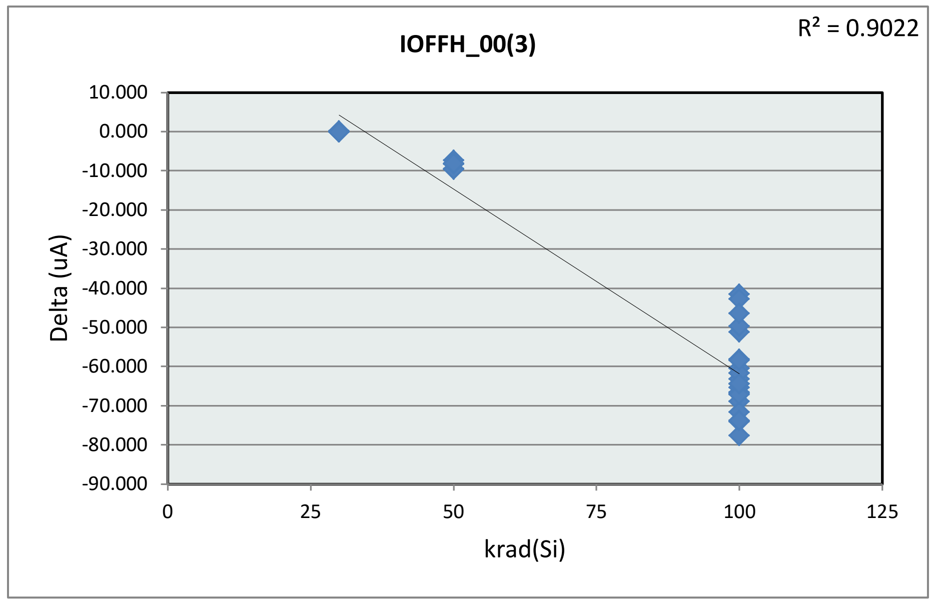
	IOFFH_00(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.766	4.541	46.790
Average	0.848	10.373	64.856
Max	0.933	13.560	78.014
UL	15.000	15.000	15.000



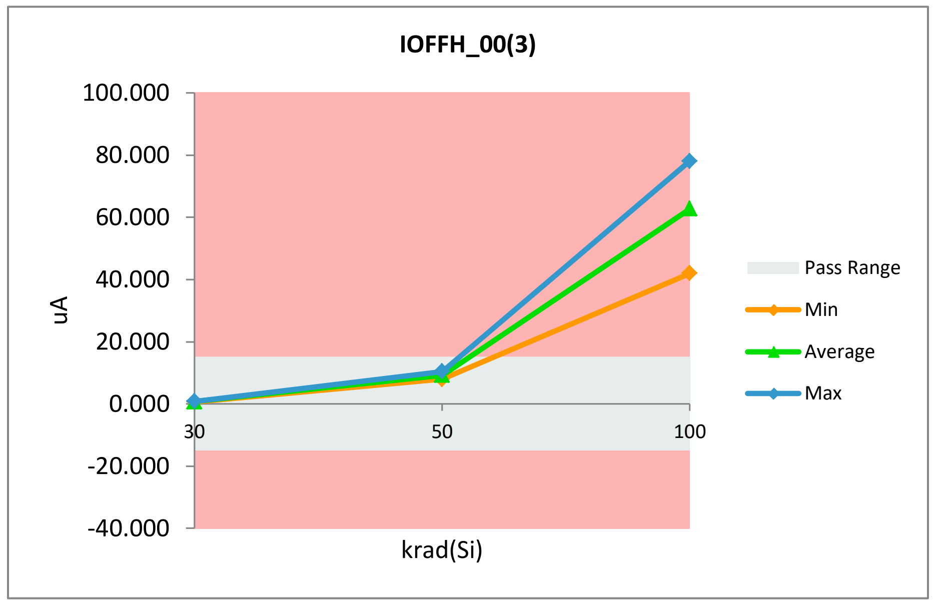
HDR TID Report T0 data
SN55LVCP22A-SP

	IOFFH_00(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	0.749	0.847	-0.099
30	2	0.618	0.773	-0.155
30	3	0.655	0.773	-0.117
30	4	0.749	0.642	0.106
30	5	0.693	0.791	-0.099
50	11	0.693	8.003	-7.310
50	12	0.637	10.112	-9.475
50	13	0.767	10.413	-9.646
50	14	0.618	8.907	-8.289
50	15	0.767	8.907	-8.140
100	22	0.415	51.616	-51.201
100	23	0.415	63.653	-63.238
100	24	0.716	58.838	-58.122
100	25	0.716	66.060	-65.344
100	26	0.716	69.671	-68.955
100	27	0.415	74.486	-74.071
100	28	0.415	78.097	-77.682
100	29	0.716	62.449	-61.733
100	30	0.415	72.078	-71.663
100	31	0.716	74.486	-73.770
100	32	0.716	67.264	-66.548
100	33	0.415	67.264	-66.849
100	34	0.415	41.987	-41.572
100	35	0.415	43.190	-42.775
100	36	0.716	61.245	-60.529
100	37	0.716	50.412	-49.696
100	38	0.415	46.801	-46.386
100	39	0.716	62.449	-61.733
100	40	0.716	74.486	-73.770
100	41	0.415	58.838	-58.423
100	42	0.114	67.264	-67.150
100	43	0.415	64.856	-64.441
100	44	0.415	64.856	-64.441
	Max	0.767	78.097	0.106
	Average	0.582	45.228	-44.646
	Min	0.114	0.642	-77.682
	Std Dev	0.167	28.299	28.366

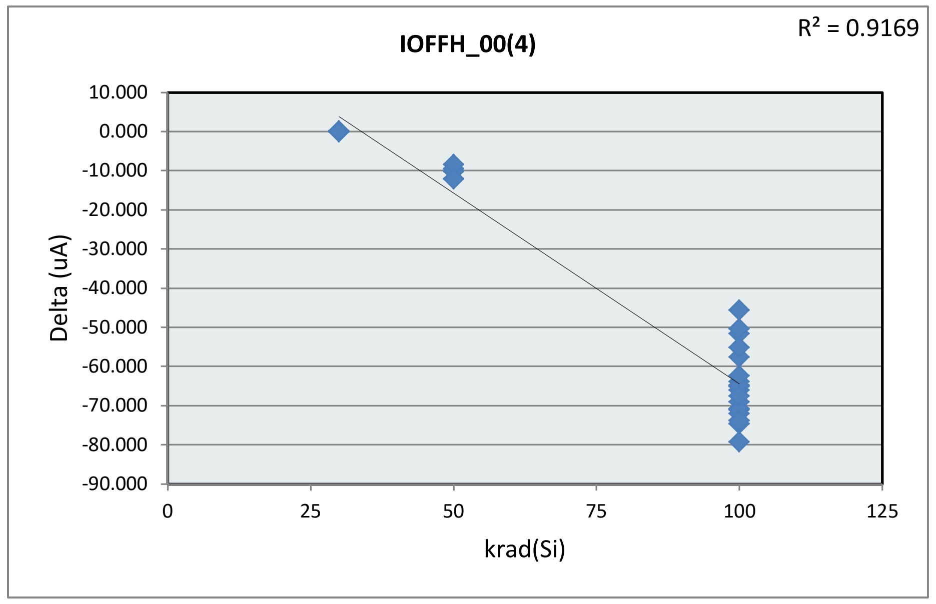


	IOFFH_00(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.642	8.003	41.987
Average	0.765	9.268	62.711
Max	0.847	10.413	78.097
UL	15.000	15.000	15.000

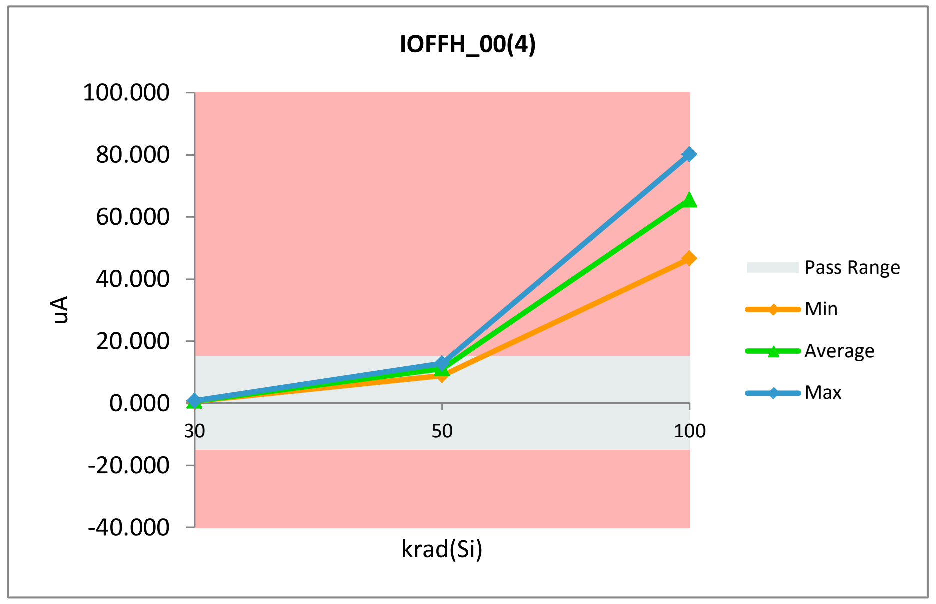


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFH_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.651	0.676	-0.026
30	2	0.613	0.602	0.011
30	3	0.781	0.695	0.086
30	4	0.781	0.788	-0.007
30	5	0.632	0.714	-0.082
50	11	0.688	12.862	-12.174
50	12	0.632	10.161	-9.529
50	13	0.818	11.061	-10.243
50	14	0.576	8.960	-8.384
50	15	0.799	12.862	-12.063
100	22	0.919	52.527	-51.608
100	23	0.919	66.925	-66.006
100	24	0.919	58.526	-57.607
100	25	0.318	69.325	-69.007
100	26	0.619	65.726	-65.107
100	27	0.619	75.325	-74.706
100	28	0.919	80.124	-79.205
100	29	0.619	64.526	-63.907
100	30	0.919	72.925	-72.006
100	31	0.619	71.725	-71.106
100	32	0.619	75.325	-74.706
100	33	0.919	71.725	-70.806
100	34	0.919	46.527	-45.608
100	35	0.919	46.527	-45.608
100	36	0.919	65.726	-64.807
100	37	0.919	56.126	-55.207
100	38	0.919	51.327	-50.408
100	39	0.919	71.725	-70.806
100	40	0.919	65.726	-64.807
100	41	0.919	63.326	-62.407
100	42	0.619	68.125	-67.506
100	43	0.318	74.125	-73.807
100	44	0.318	74.125	-73.807
	Max	0.919	80.124	0.086
	Average	0.742	47.499	-46.757
	Min	0.318	0.602	-79.205
	Std Dev	0.190	29.075	29.068



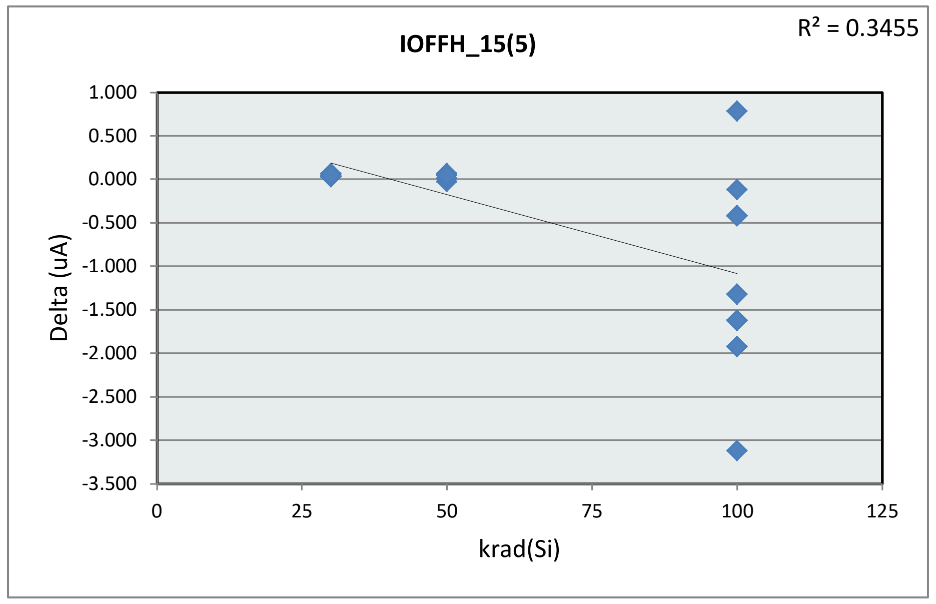
	IOFFH_00(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.602	8.960	46.527
Average	0.695	11.181	65.569
Max	0.788	12.862	80.124
UL	15.000	15.000	15.000



HDR TID Report T0 data
SN55LVCP22A-SP

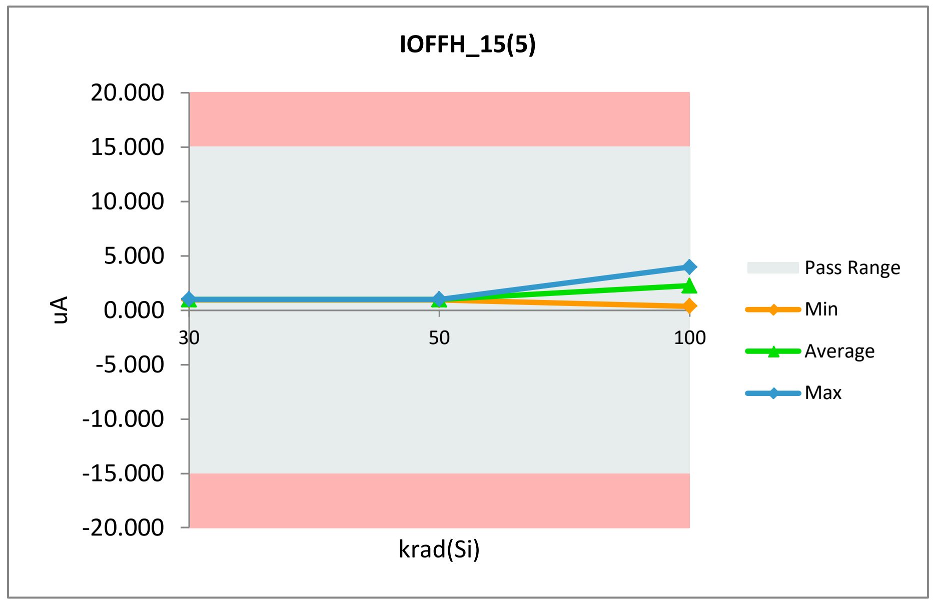
	IOFFH_15(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.026	0.997	0.029
30	2	1.008	0.942	0.066
30	3	1.045	1.016	0.029
30	4	1.026	0.997	0.029
30	5	1.045	0.997	0.048
50	11	0.989	1.016	-0.027
50	12	1.026	0.960	0.066
50	13	1.064	0.997	0.066
50	14	0.952	0.942	0.010
50	15	1.064	1.016	0.048
100	22	1.146	1.567	-0.421
100	23	1.146	0.366	0.780
100	24	1.446	2.767	-1.321
100	25	1.146	1.567	-0.421
100	26	1.146	2.767	-1.621
100	27	0.845	3.967	-3.122
100	28	1.146	2.767	-1.621
100	29	0.845	2.767	-1.922
100	30	0.845	2.767	-1.922
100	31	0.845	2.767	-1.922
100	32	1.146	2.767	-1.621
100	33	1.146	1.567	-0.421
100	34	1.146	1.567	-0.421
100	35	1.146	2.767	-1.621
100	36	1.146	1.567	-0.421
100	37	1.146	2.767	-1.621
100	38	1.146	1.567	-0.421
100	39	1.446	1.567	-0.121
100	40	1.446	2.767	-1.321
100	41	1.146	2.767	-1.621
100	42	1.446	2.767	-1.321
100	43	1.146	1.567	-0.421
100	44	1.146	1.567	-0.421
	Max	1.446	3.967	0.780
	Average	1.109	1.864	-0.755
	Min	0.845	0.366	-3.122
	Std Dev	0.162	0.883	0.885



	IOFFH_15(5)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	15	uA
Min Limit	-15	uA

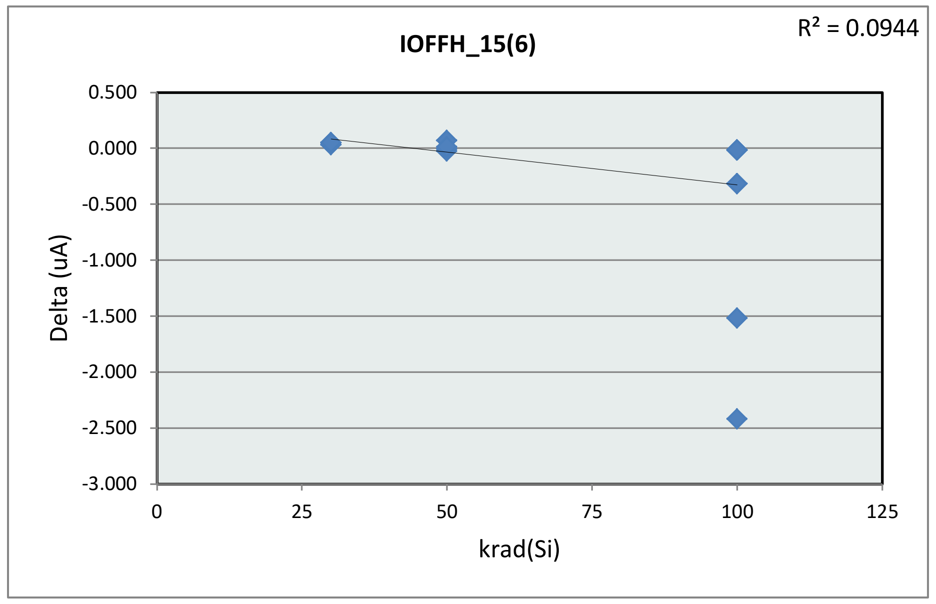
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.942	0.942	0.366
Average	0.990	0.986	2.245
Max	1.016	1.016	3.967
UL	15.000	15.000	15.000



HDR TID Report T0 data
SN55LVCP22A-SP

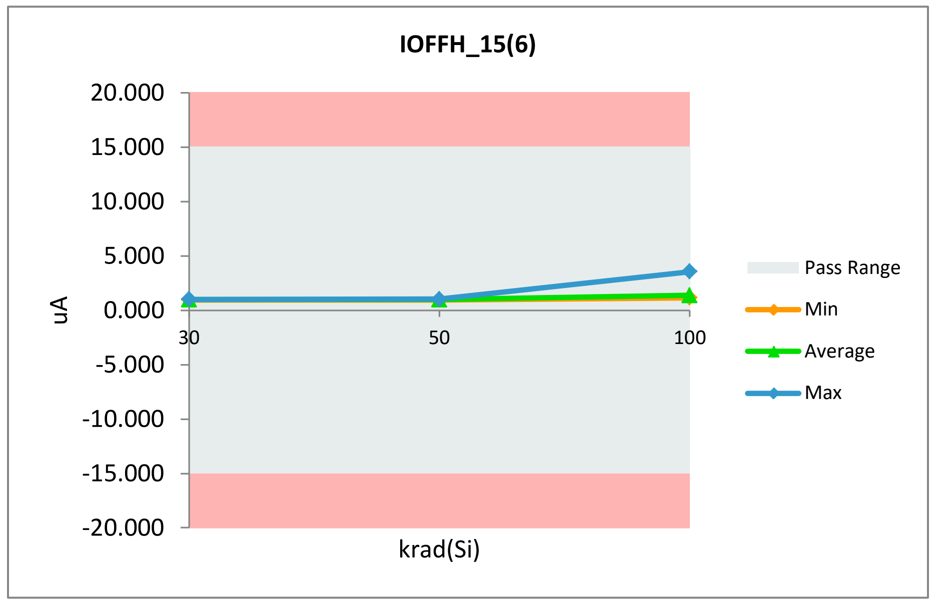
	IOFFH_15(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.037	0.989	0.048
30	2	0.981	0.952	0.029
30	3	1.056	1.008	0.048
30	4	1.018	0.989	0.029
30	5	1.037	0.989	0.048
50	11	0.981	1.008	-0.027
50	12	1.018	0.952	0.067
50	13	1.056	0.989	0.067
50	14	0.944	0.952	-0.008
50	15	1.037	1.026	0.011
100	22	0.835	1.154	-0.319
100	23	1.135	1.154	-0.019
100	24	0.835	1.154	-0.319
100	25	1.135	1.154	-0.019
100	26	1.135	1.154	-0.019
100	27	1.135	3.556	-2.421
100	28	1.135	1.154	-0.019
100	29	0.835	2.355	-1.520
100	30	1.135	1.154	-0.019
100	31	1.135	1.154	-0.019
100	32	0.835	1.154	-0.319
100	33	1.135	1.154	-0.019
100	34	1.135	1.154	-0.019
100	35	1.135	1.154	-0.019
100	36	1.135	1.154	-0.019
100	37	0.835	1.154	-0.319
100	38	1.135	1.154	-0.019
100	39	1.135	1.154	-0.019
100	40	0.835	2.355	-1.520
100	41	1.135	1.154	-0.019
100	42	1.135	1.154	-0.019
100	43	0.835	1.154	-0.319
100	44	0.835	1.154	-0.319
	Max	1.135	3.556	0.067
	Average	1.026	1.248	-0.222
	Min	0.835	0.952	-2.421
	Std Dev	0.123	0.520	0.545



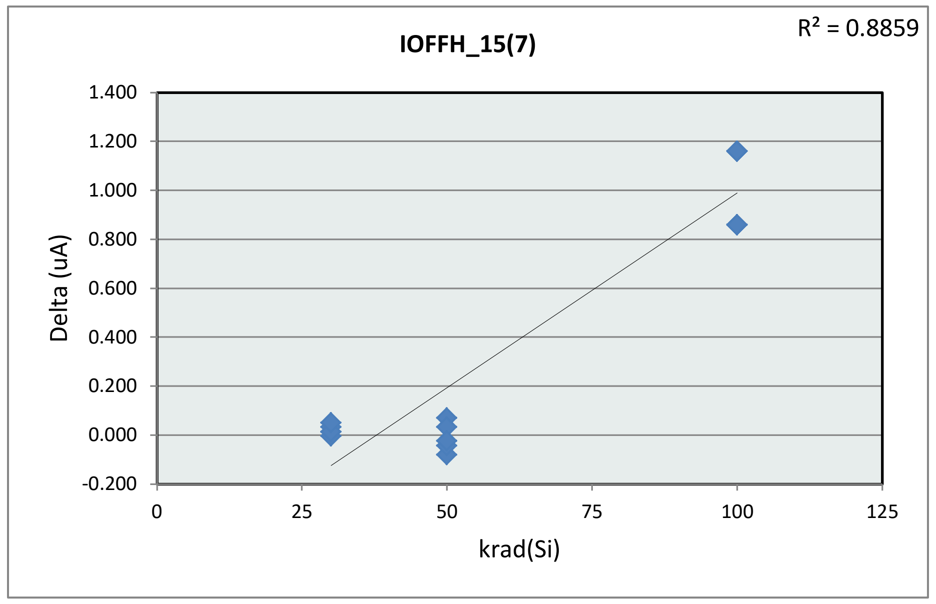
	IOFFH_15(6)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	15	uA
Min Limit	-15	uA

krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.952	0.952	1.154
Average	0.985	0.985	1.363
Max	1.008	1.026	3.556
UL	15.000	15.000	15.000

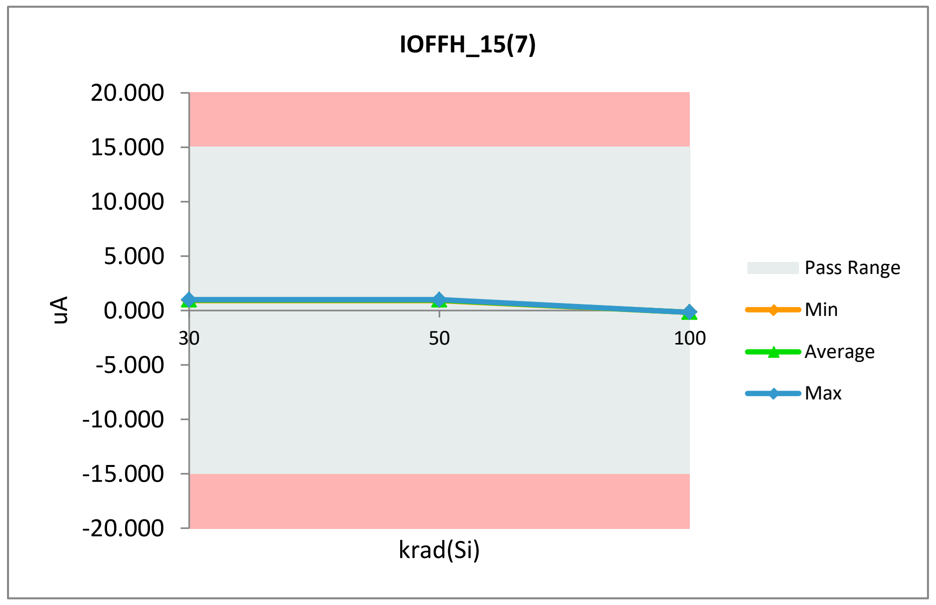


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFH_15(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.010	0.978	0.032
30	2	0.954	0.941	0.013
30	3	0.991	0.996	-0.005
30	4	0.991	0.978	0.013
30	5	1.010	0.959	0.051
50	11	0.935	1.015	-0.080
50	12	0.991	0.922	0.069
50	13	1.029	0.996	0.032
50	14	0.898	0.941	-0.043
50	15	0.991	1.015	-0.024
100	22	0.716	-0.142	0.858
100	23	0.716	-0.142	0.858
100	24	0.716	-0.142	0.858
100	25	1.017	-0.142	1.159
100	26	0.716	-0.142	0.858
100	27	0.716	-0.142	0.858
100	28	0.716	-0.142	0.858
100	29	1.017	-0.142	1.159
100	30	1.017	-0.142	1.159
100	31	1.017	-0.142	1.159
100	32	0.716	-0.142	0.858
100	33	0.716	-0.142	0.858
100	34	0.716	-0.142	0.858
100	35	1.017	-0.142	1.159
100	36	1.017	-0.142	1.159
100	37	0.716	-0.142	0.858
100	38	0.716	-0.142	0.858
100	39	1.017	-0.142	1.159
100	40	1.017	-0.142	1.159
100	41	0.716	-0.142	0.858
100	42	1.017	-0.142	1.159
100	43	1.017	-0.142	1.159
100	44	1.017	-0.142	1.159
	Max	1.029	1.015	1.159
	Average	0.896	0.196	0.700
	Min	0.716	-0.142	-0.080
	Std Dev	0.141	0.521	0.482

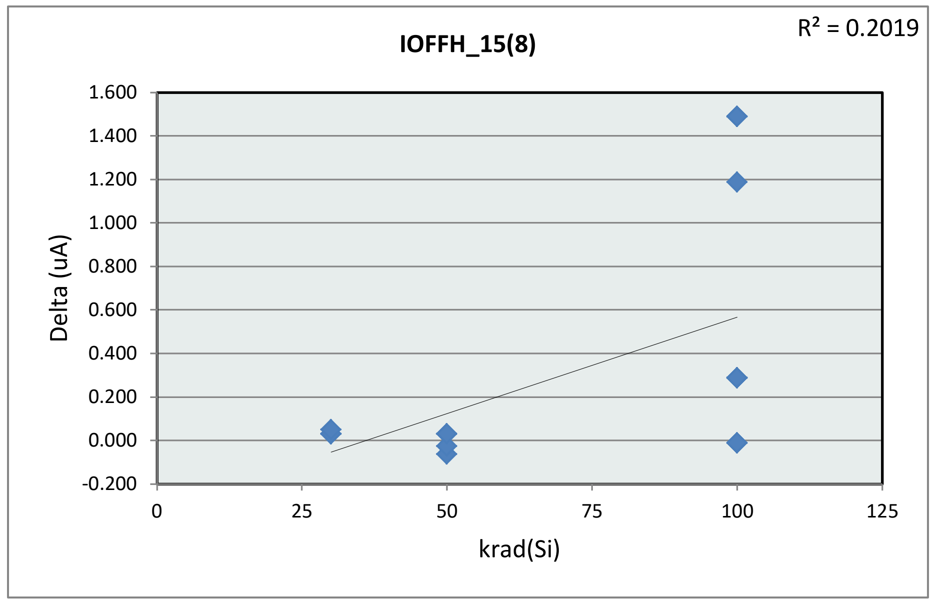


	IOFFH_15(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.941	0.922	-0.142
Average	0.970	0.978	-0.142
Max	0.996	1.015	-0.142
UL	15.000	15.000	15.000

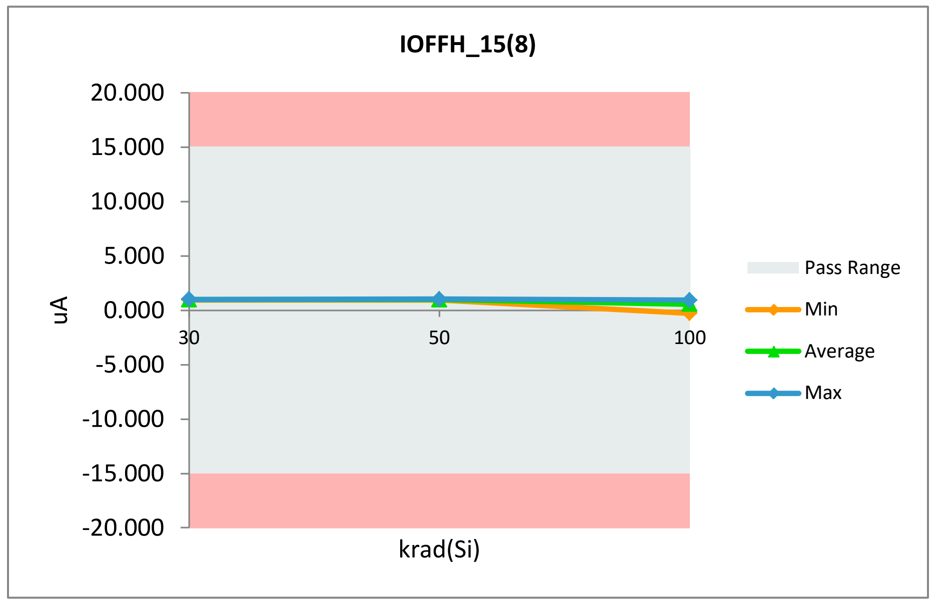


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFH_15(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.041	1.011	0.030
30	2	0.985	0.955	0.030
30	3	1.023	0.993	0.030
30	4	1.023	0.993	0.030
30	5	1.041	0.993	0.049
50	11	0.967	1.030	-0.063
50	12	1.004	0.974	0.030
50	13	1.041	1.011	0.030
50	14	0.930	0.955	-0.026
50	15	1.023	0.993	0.030
100	22	1.219	-0.269	1.488
100	23	0.919	-0.269	1.188
100	24	1.219	0.931	0.288
100	25	0.919	0.931	-0.012
100	26	1.219	0.931	0.288
100	27	0.919	0.931	-0.012
100	28	1.219	0.931	0.288
100	29	1.219	0.931	0.288
100	30	1.219	0.931	0.288
100	31	0.919	0.931	-0.012
100	32	1.219	-0.269	1.488
100	33	0.919	0.931	-0.012
100	34	1.219	0.931	0.288
100	35	1.219	0.931	0.288
100	36	1.219	0.931	0.288
100	37	1.219	0.931	0.288
100	38	0.919	0.931	-0.012
100	39	1.219	0.931	0.288
100	40	1.219	-0.269	1.488
100	41	1.219	0.931	0.288
100	42	1.219	-0.269	1.488
100	43	1.219	-0.269	1.488
100	44	1.219	-0.269	1.488
	Max	1.219	1.030	1.488
	Average	1.100	0.694	0.406
	Min	0.919	-0.269	-0.063
	Std Dev	0.129	0.509	0.564



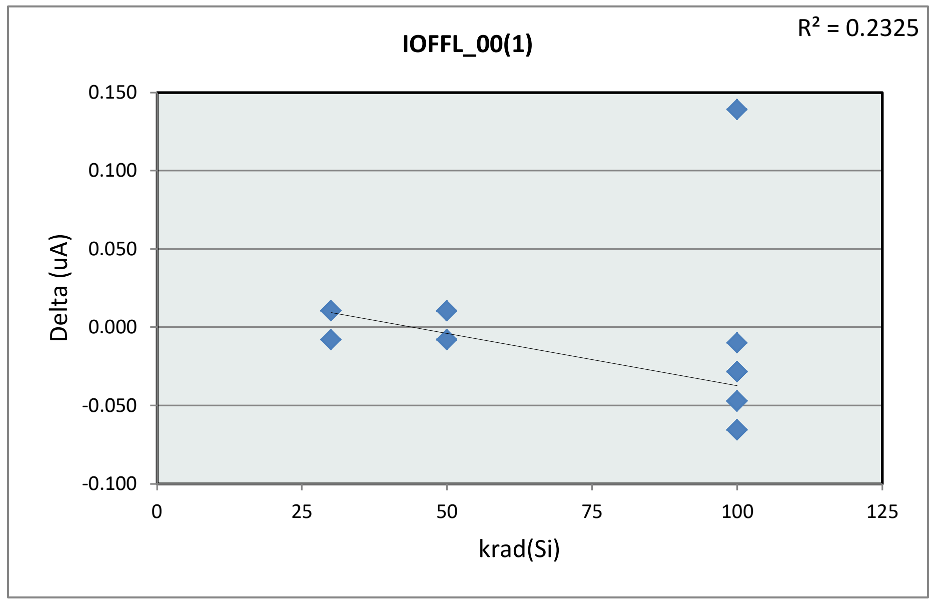
	IOFFH_15(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.955	0.955	-0.269
Average	0.989	0.993	0.566
Max	1.011	1.030	0.931
UL	15.000	15.000	15.000



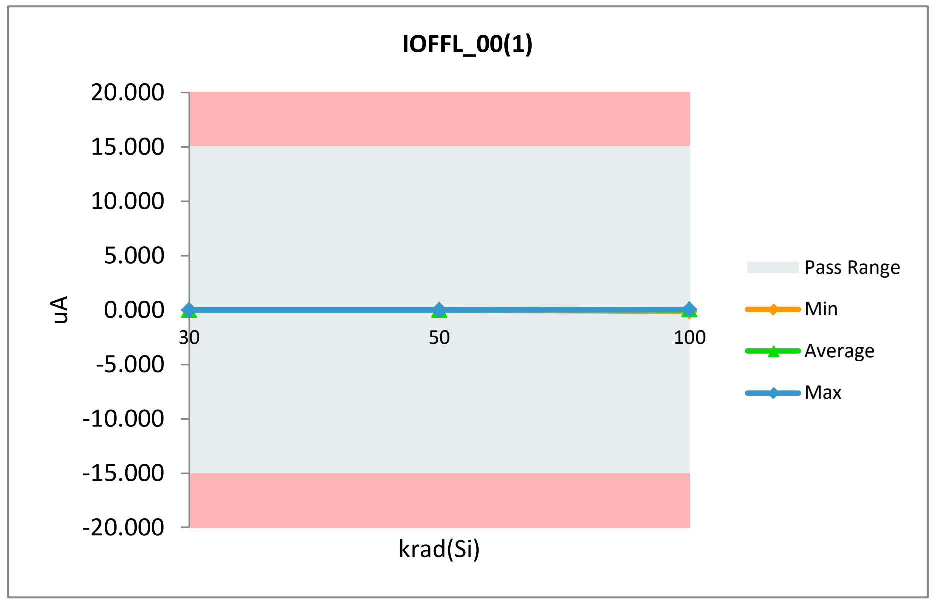
HDR TID Report T0 data
SN55LVCP22A-SP

	IOFFL_00(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.003	0.011	-0.008
30	2	0.003	-0.007	0.011
30	3	0.003	-0.007	0.011
30	4	0.003	-0.007	0.011
30	5	0.003	-0.007	0.011
50	11	0.003	0.011	-0.008
50	12	0.003	-0.007	0.011
50	13	0.003	0.011	-0.008
50	14	0.003	0.011	-0.008
50	15	0.003	-0.007	0.011
100	22	-0.028	0.019	-0.047
100	23	-0.028	0.019	-0.047
100	24	-0.028	0.000	-0.029
100	25	-0.028	0.000	-0.029
100	26	-0.028	0.019	-0.047
100	27	-0.010	-0.148	0.139
100	28	-0.028	0.038	-0.066
100	29	-0.010	0.019	-0.029
100	30	-0.028	0.019	-0.047
100	31	-0.028	0.019	-0.047
100	32	-0.010	0.000	-0.010
100	33	-0.010	0.019	-0.029
100	34	-0.028	0.019	-0.047
100	35	-0.028	0.019	-0.047
100	36	-0.010	0.038	-0.047
100	37	-0.028	0.038	-0.066
100	38	-0.028	0.000	-0.029
100	39	-0.028	0.038	-0.066
100	40	-0.028	0.019	-0.047
100	41	-0.028	0.019	-0.047
100	42	-0.028	0.019	-0.047
100	43	-0.028	0.038	-0.066
100	44	-0.028	0.038	-0.066
	Max	0.003	0.038	0.139
	Average	-0.016	0.009	-0.025
	Min	-0.028	-0.148	-0.066
	Std Dev	0.014	0.032	0.039

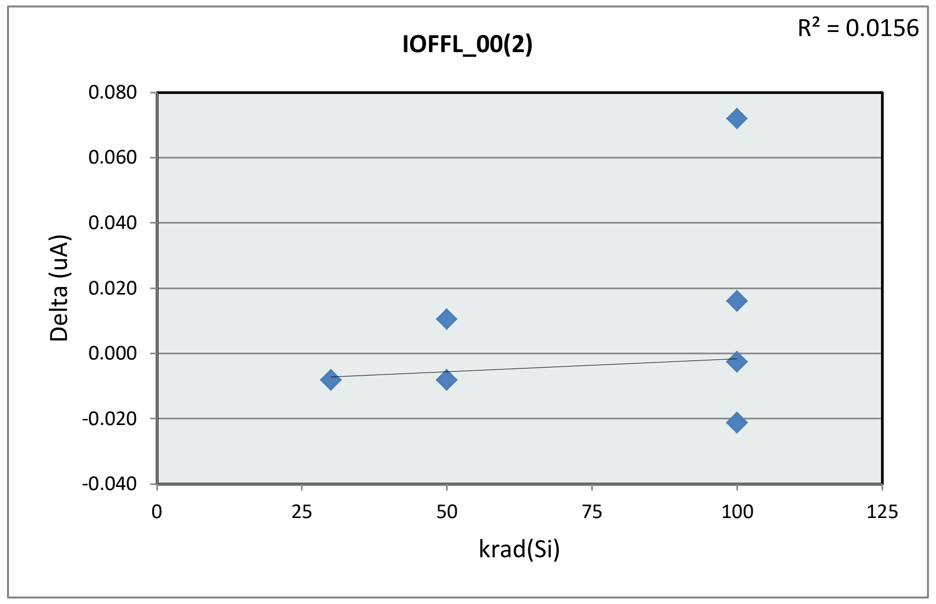


	IOFFL_00(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.007	-0.007	-0.148
Average	-0.003	0.004	0.013
Max	0.011	0.011	0.038
UL	15.000	15.000	15.000

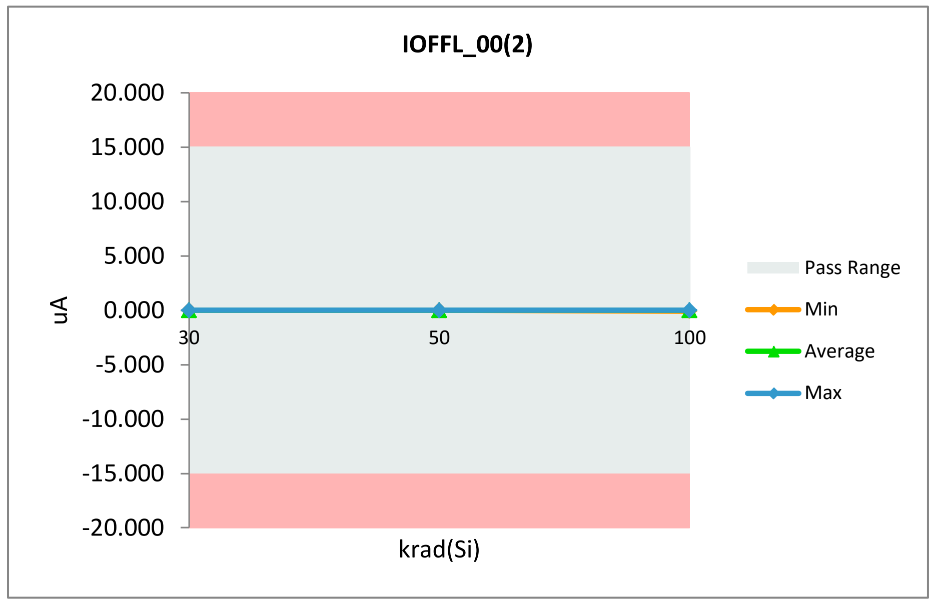


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFL_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.005	0.003	-0.008
30	2	-0.005	0.003	-0.008
30	3	-0.005	0.003	-0.008
30	4	-0.005	0.003	-0.008
30	5	-0.005	0.003	-0.008
50	11	-0.005	0.003	-0.008
50	12	-0.005	0.003	-0.008
50	13	-0.005	0.003	-0.008
50	14	-0.005	0.003	-0.008
50	15	0.013	0.003	0.011
100	22	0.008	-0.008	0.016
100	23	-0.010	-0.008	-0.003
100	24	-0.010	0.011	-0.021
100	25	-0.010	-0.008	-0.003
100	26	0.008	0.011	-0.003
100	27	-0.010	-0.082	0.072
100	28	-0.010	-0.008	-0.003
100	29	-0.010	-0.008	-0.003
100	30	0.008	-0.008	0.016
100	31	-0.010	-0.008	-0.003
100	32	0.008	0.011	-0.003
100	33	-0.010	0.011	-0.021
100	34	-0.010	0.011	-0.021
100	35	-0.010	-0.008	-0.003
100	36	0.008	0.011	-0.003
100	37	-0.010	0.011	-0.021
100	38	0.008	-0.008	0.016
100	39	0.008	-0.008	0.016
100	40	0.008	-0.008	0.016
100	41	-0.010	0.011	-0.021
100	42	-0.010	0.011	-0.021
100	43	-0.010	0.011	-0.021
100	44	-0.010	0.011	-0.021
	Max	0.013	0.011	0.072
	Average	-0.004	-0.001	-0.003
	Min	-0.010	-0.082	-0.021
	Std Dev	0.008	0.017	0.018

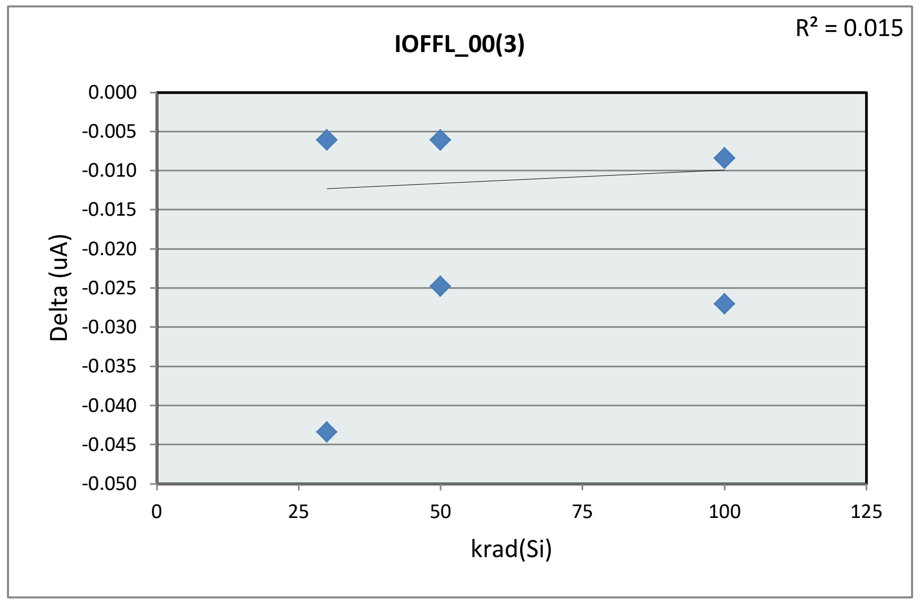


	IOFFL_00(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.003	0.003	-0.082
Average	0.003	0.003	-0.002
Max	0.003	0.003	0.011
UL	15.000	15.000	15.000

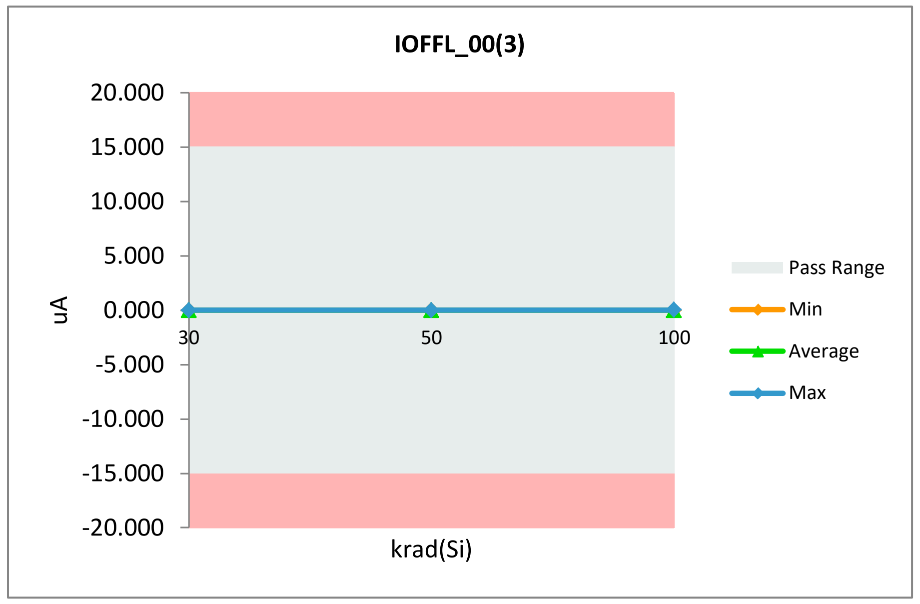


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFL_00(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.035	0.009	-0.043
30	2	-0.016	-0.010	-0.006
30	3	-0.016	-0.010	-0.006
30	4	-0.016	-0.010	-0.006
30	5	-0.016	-0.010	-0.006
50	11	-0.016	-0.010	-0.006
50	12	-0.016	0.009	-0.025
50	13	-0.016	-0.010	-0.006
50	14	-0.016	-0.010	-0.006
50	15	-0.016	-0.010	-0.006
100	22	-0.002	0.025	-0.027
100	23	-0.002	0.006	-0.008
100	24	-0.002	0.006	-0.008
100	25	-0.002	0.006	-0.008
100	26	-0.002	0.006	-0.008
100	27	-0.002	0.006	-0.008
100	28	-0.002	0.006	-0.008
100	29	-0.021	0.006	-0.027
100	30	-0.002	0.006	-0.008
100	31	-0.002	0.006	-0.008
100	32	-0.002	0.006	-0.008
100	33	-0.002	0.006	-0.008
100	34	-0.002	0.006	-0.008
100	35	-0.002	0.006	-0.008
100	36	-0.002	0.006	-0.008
100	37	-0.002	0.006	-0.008
100	38	-0.002	0.006	-0.008
100	39	-0.002	0.006	-0.008
100	40	-0.002	0.006	-0.008
100	41	-0.002	0.006	-0.008
100	42	-0.002	0.006	-0.008
100	43	-0.002	0.006	-0.008
100	44	-0.002	0.006	-0.008
	Max	-0.002	0.025	-0.006
	Average	-0.007	0.003	-0.011
	Min	-0.035	-0.010	-0.043
	Std Dev	0.008	0.008	0.008

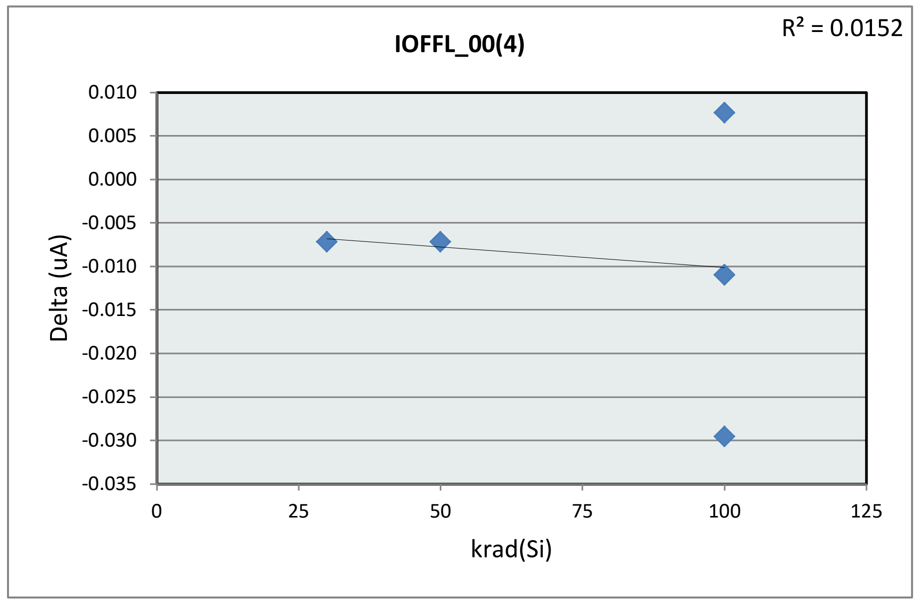


	IOFFL_00(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.010	-0.010	0.006
Average	-0.006	-0.006	0.007
Max	0.009	0.009	0.025
UL	15.000	15.000	15.000

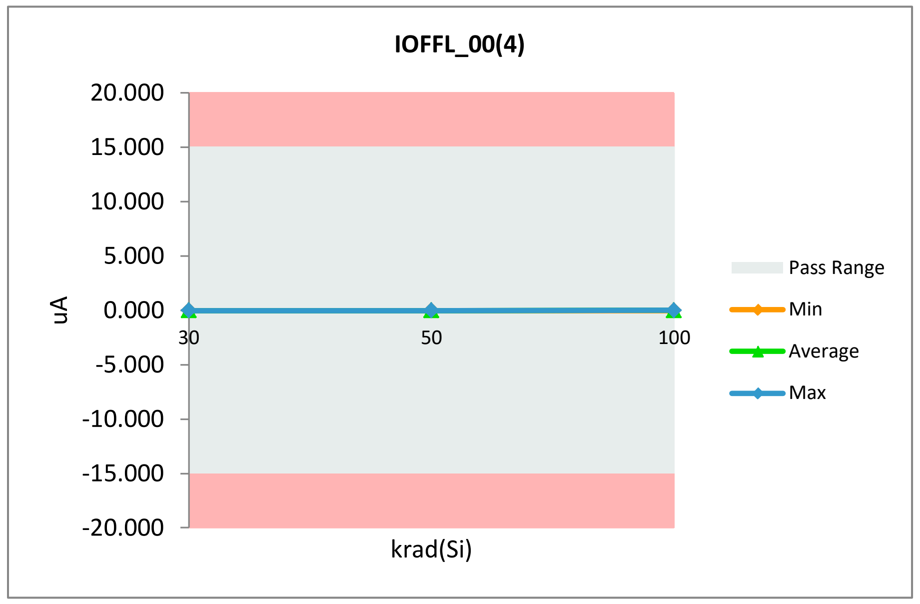


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFL_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-0.019	-0.012	-0.007
30	2	-0.019	-0.012	-0.007
30	3	-0.019	-0.012	-0.007
30	4	-0.019	-0.012	-0.007
30	5	-0.019	-0.012	-0.007
50	11	-0.019	-0.012	-0.007
50	12	-0.019	-0.012	-0.007
50	13	-0.019	-0.012	-0.007
50	14	-0.019	-0.012	-0.007
50	15	-0.019	-0.012	-0.007
100	22	-0.007	0.004	-0.011
100	23	-0.007	0.004	-0.011
100	24	-0.026	0.004	-0.030
100	25	-0.007	0.004	-0.011
100	26	-0.026	0.004	-0.030
100	27	-0.007	0.004	-0.011
100	28	-0.007	-0.015	0.008
100	29	-0.007	0.004	-0.011
100	30	-0.007	0.004	-0.011
100	31	-0.007	0.004	-0.011
100	32	-0.007	0.004	-0.011
100	33	-0.007	0.004	-0.011
100	34	-0.026	0.004	-0.030
100	35	-0.007	0.004	-0.011
100	36	-0.026	0.004	-0.030
100	37	-0.026	0.004	-0.030
100	38	-0.007	-0.015	0.008
100	39	-0.007	0.004	-0.011
100	40	-0.007	0.004	-0.011
100	41	-0.007	-0.015	0.008
100	42	-0.007	-0.015	0.008
100	43	-0.007	-0.015	0.008
100	44	-0.007	-0.015	0.008
	Max	-0.007	0.004	0.008
	Average	-0.014	-0.004	-0.009
	Min	-0.026	-0.015	-0.030
	Std Dev	0.007	0.009	0.011

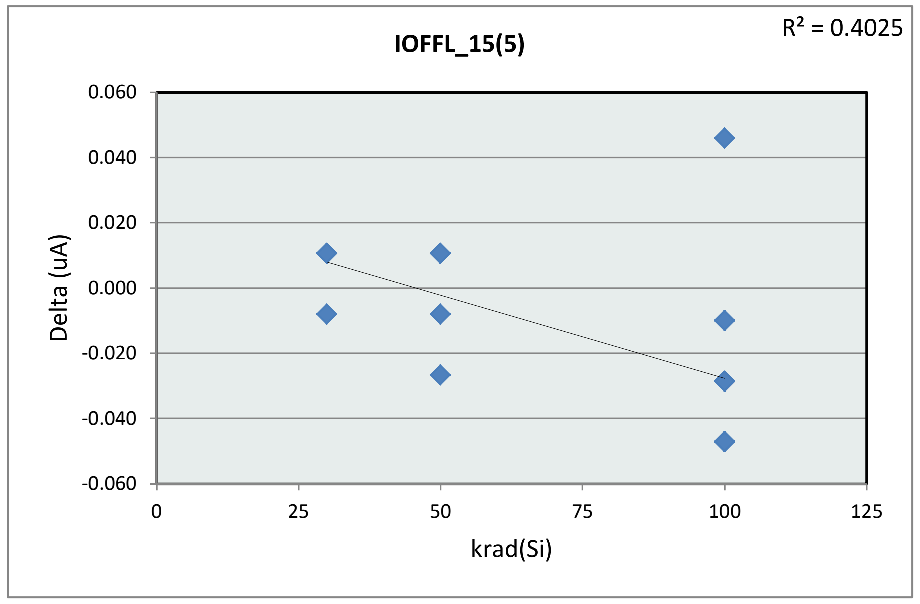


	IOFFL_00(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.012	-0.012	-0.015
Average	-0.012	-0.012	-0.001
Max	-0.012	-0.012	0.004
UL	15.000	15.000	15.000

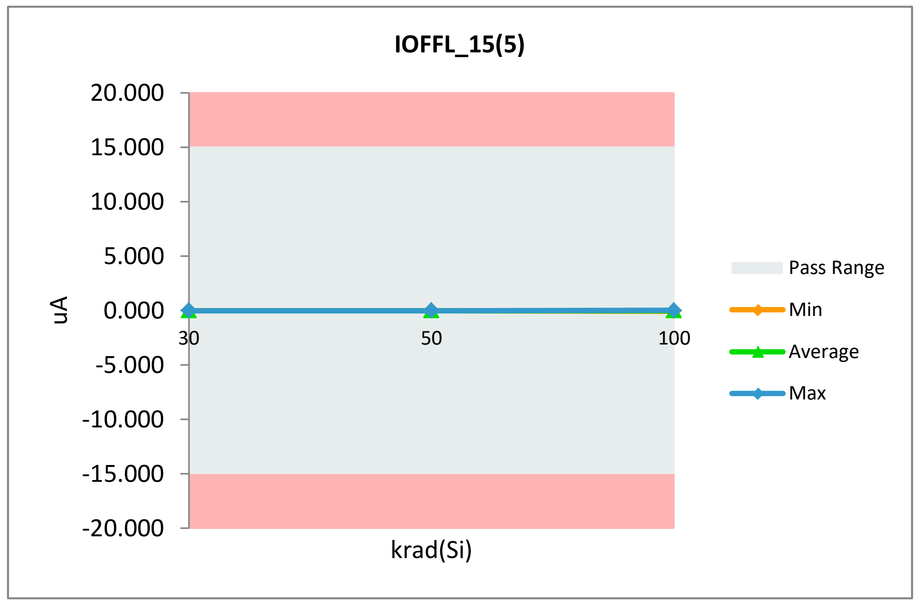


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFL_15(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	0.003	-0.007	0.011
30	2	0.003	-0.007	0.011
30	3	0.003	-0.007	0.011
30	4	0.003	0.011	-0.008
30	5	0.003	-0.007	0.011
50	11	0.003	-0.007	0.011
50	12	0.003	0.011	-0.008
50	13	0.003	-0.007	0.011
50	14	-0.015	0.011	-0.027
50	15	0.003	-0.007	0.011
100	22	-0.028	0.000	-0.029
100	23	-0.028	0.019	-0.047
100	24	-0.028	0.000	-0.029
100	25	-0.010	0.019	-0.029
100	26	-0.028	0.000	-0.029
100	27	-0.010	-0.055	0.046
100	28	-0.028	0.019	-0.047
100	29	-0.028	0.019	-0.047
100	30	-0.028	0.019	-0.047
100	31	-0.010	0.000	-0.010
100	32	-0.028	0.000	-0.029
100	33	-0.010	0.000	-0.010
100	34	-0.028	0.000	-0.029
100	35	-0.028	0.019	-0.047
100	36	-0.010	0.019	-0.029
100	37	-0.010	0.019	-0.029
100	38	-0.028	0.000	-0.029
100	39	-0.010	0.000	-0.010
100	40	-0.028	0.019	-0.047
100	41	-0.028	0.000	-0.029
100	42	-0.010	0.019	-0.029
100	43	-0.028	0.000	-0.029
100	44	-0.028	0.000	-0.029
	Max	0.003	0.019	0.046
	Average	-0.015	0.004	-0.018
	Min	-0.028	-0.055	-0.047
	Std Dev	0.014	0.015	0.023



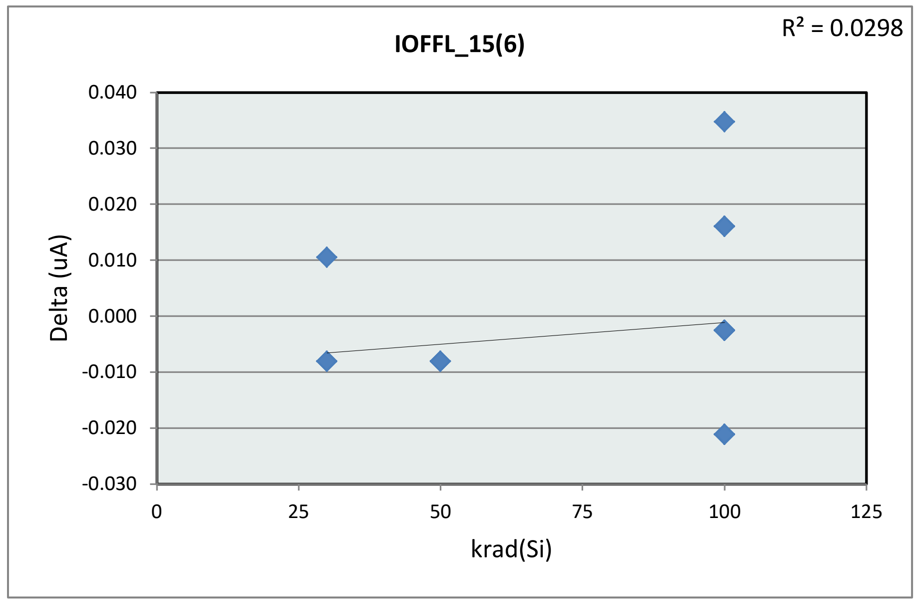
	IOFFL_15(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.007	-0.007	-0.055
Average	-0.003	0.000	0.006
Max	0.011	0.011	0.019
UL	15.000	15.000	15.000



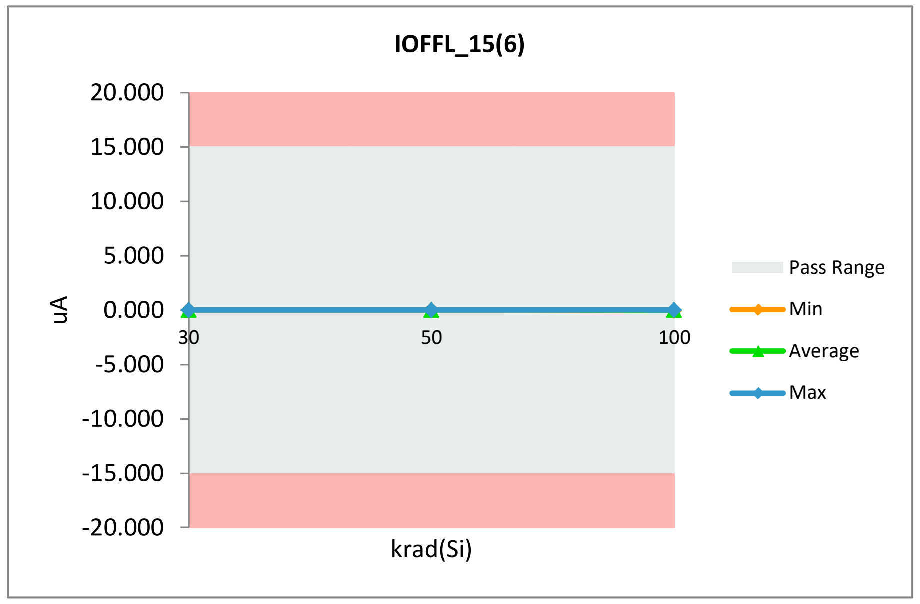
HDR TID Report T0 data
SN55LVCP22A-SP

	IOFFL_15(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-0.005	0.003	-0.008
30	2	-0.005	0.003	-0.008
30	3	-0.005	0.003	-0.008
30	4	-0.005	0.003	-0.008
30	5	0.013	0.003	0.011
50	11	-0.005	0.003	-0.008
50	12	-0.005	0.003	-0.008
50	13	-0.005	0.003	-0.008
50	14	-0.005	0.003	-0.008
50	15	-0.005	0.003	-0.008
100	22	-0.010	-0.008	-0.003
100	23	0.008	-0.008	0.016
100	24	-0.010	0.011	-0.021
100	25	-0.010	-0.008	-0.003
100	26	-0.010	-0.008	-0.003
100	27	-0.010	-0.045	0.035
100	28	-0.010	0.011	-0.021
100	29	0.008	0.011	-0.003
100	30	-0.010	0.011	-0.021
100	31	0.008	0.011	-0.003
100	32	-0.010	-0.008	-0.003
100	33	0.008	-0.008	0.016
100	34	0.008	0.011	-0.003
100	35	-0.010	0.011	-0.021
100	36	0.008	0.011	-0.003
100	37	-0.010	-0.008	-0.003
100	38	-0.010	-0.008	-0.003
100	39	0.008	-0.008	0.016
100	40	-0.010	0.011	-0.021
100	41	-0.010	-0.008	-0.003
100	42	-0.010	-0.008	-0.003
100	43	0.008	-0.008	0.016
100	44	0.008	-0.008	0.016
	Max	0.013	0.011	0.035
	Average	-0.003	-0.001	-0.003
	Min	-0.010	-0.045	-0.021
	Std Dev	0.008	0.011	0.013

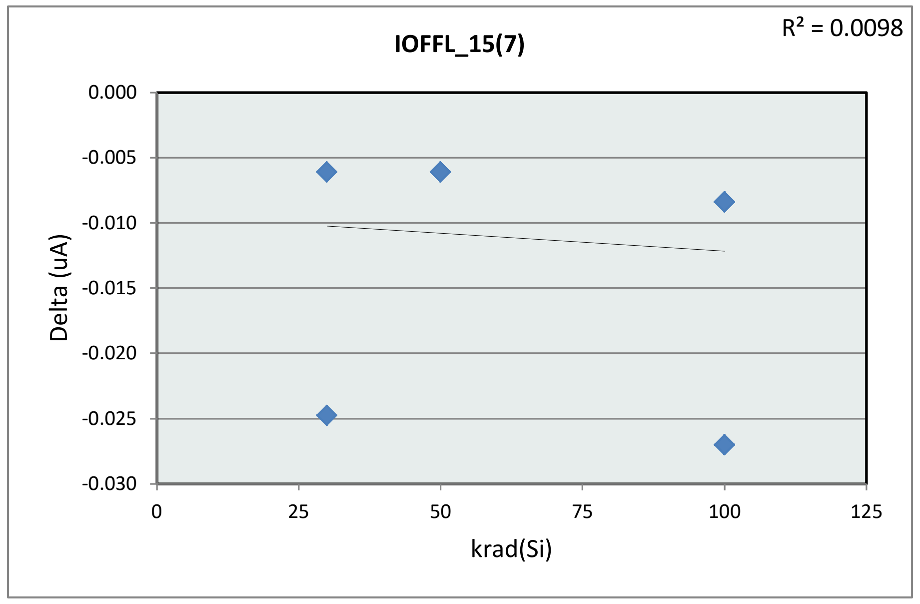


	IOFFL_15(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	0.003	0.003	-0.045
Average	0.003	0.003	-0.002
Max	0.003	0.003	0.011
UL	15.000	15.000	15.000

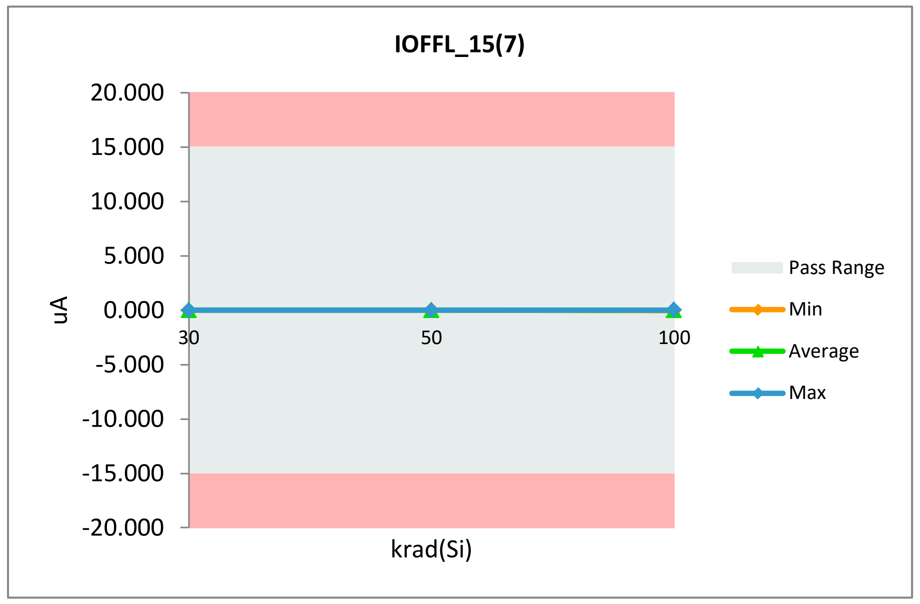


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFL_15(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.016	-0.010	-0.006
30	2	-0.016	0.009	-0.025
30	3	-0.016	0.009	-0.025
30	4	-0.016	-0.010	-0.006
30	5	-0.016	-0.010	-0.006
50	11	-0.016	-0.010	-0.006
50	12	-0.016	-0.010	-0.006
50	13	-0.016	-0.010	-0.006
50	14	-0.016	-0.010	-0.006
50	15	-0.016	-0.010	-0.006
100	22	-0.002	0.006	-0.008
100	23	-0.002	0.006	-0.008
100	24	-0.002	0.006	-0.008
100	25	-0.002	0.025	-0.027
100	26	-0.002	0.006	-0.008
100	27	-0.002	0.006	-0.008
100	28	-0.002	0.006	-0.008
100	29	-0.002	0.006	-0.008
100	30	-0.002	0.006	-0.008
100	31	-0.002	0.006	-0.008
100	32	-0.002	0.006	-0.008
100	33	-0.021	0.006	-0.027
100	34	-0.002	0.006	-0.008
100	35	-0.002	0.025	-0.027
100	36	-0.002	0.006	-0.008
100	37	-0.002	0.006	-0.008
100	38	-0.021	-0.012	-0.008
100	39	-0.002	0.006	-0.008
100	40	-0.002	0.006	-0.008
100	41	-0.002	0.006	-0.008
100	42	-0.002	0.006	-0.008
100	43	-0.002	0.025	-0.027
100	44	-0.002	0.025	-0.027
	Max	-0.002	0.025	-0.006
	Average	-0.007	0.004	-0.012
	Min	-0.021	-0.012	-0.027
	Std Dev	0.007	0.011	0.008

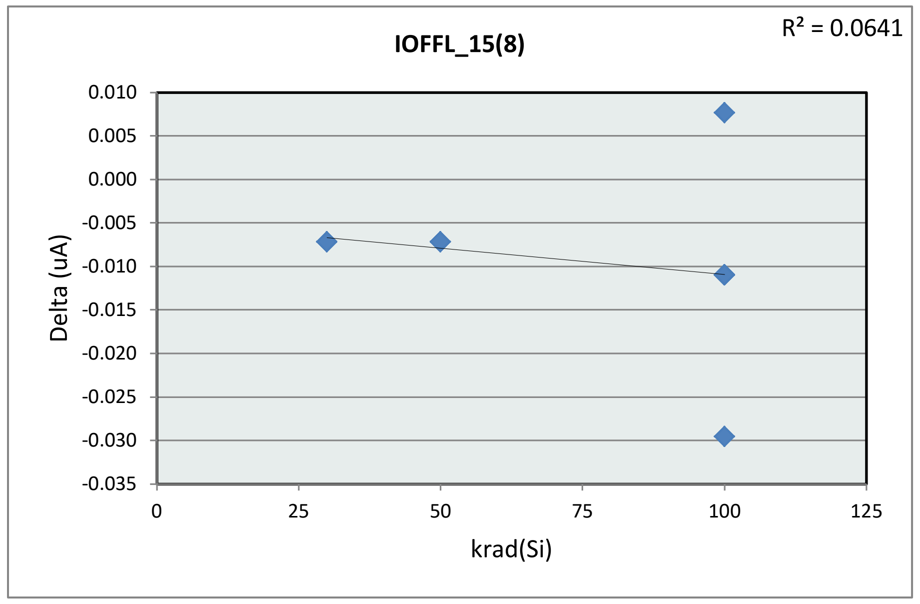


	IOFFL_15(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.010	-0.010	-0.012
Average	-0.002	-0.010	0.009
Max	0.009	-0.010	0.025
UL	15.000	15.000	15.000

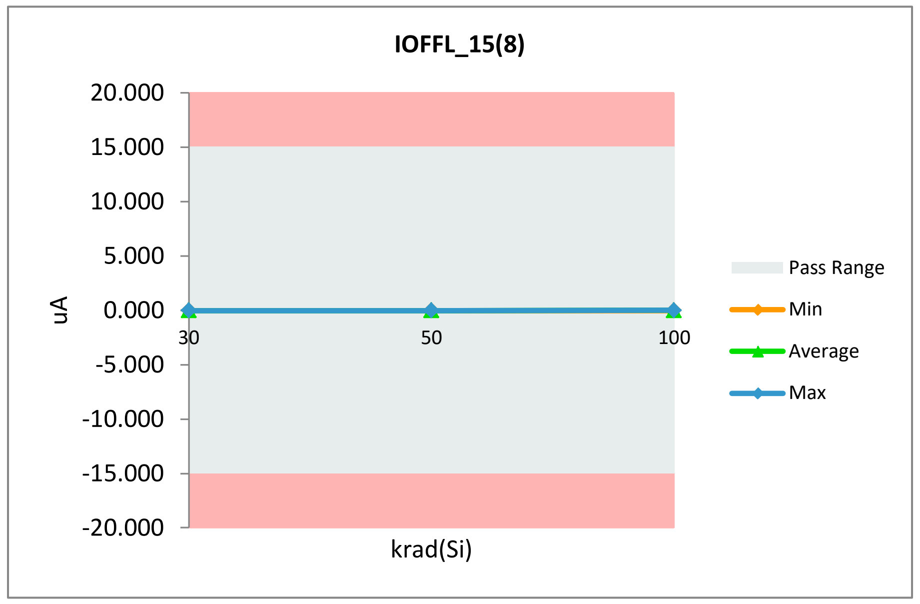


HDR TID Report T0 data
SN55LVCP22A-SP

		IOFFL_15(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.019	-0.012	-0.007
30	2	-0.019	-0.012	-0.007
30	3	-0.019	-0.012	-0.007
30	4	-0.019	-0.012	-0.007
30	5	-0.019	-0.012	-0.007
50	11	-0.019	-0.012	-0.007
50	12	-0.019	-0.012	-0.007
50	13	-0.019	-0.012	-0.007
50	14	-0.019	-0.012	-0.007
50	15	-0.019	-0.012	-0.007
100	22	-0.026	0.004	-0.030
100	23	-0.007	0.004	-0.011
100	24	-0.007	0.004	-0.011
100	25	-0.007	0.004	-0.011
100	26	-0.007	0.004	-0.011
100	27	-0.007	-0.015	0.008
100	28	-0.007	0.004	-0.011
100	29	-0.007	0.004	-0.011
100	30	-0.007	-0.015	0.008
100	31	-0.007	0.004	-0.011
100	32	-0.007	0.004	-0.011
100	33	-0.007	0.004	-0.011
100	34	-0.007	0.004	-0.011
100	35	-0.007	0.004	-0.011
100	36	-0.007	0.004	-0.011
100	37	-0.007	0.004	-0.011
100	38	-0.007	0.004	-0.011
100	39	-0.007	0.004	-0.011
100	40	-0.007	0.004	-0.011
100	41	-0.007	0.004	-0.011
100	42	-0.026	0.004	-0.030
100	43	-0.007	0.004	-0.011
100	44	-0.007	0.004	-0.011
	Max	-0.007	0.004	0.008
	Average	-0.012	-0.002	-0.010
	Min	-0.026	-0.015	-0.030
	Std Dev	0.007	0.008	0.007

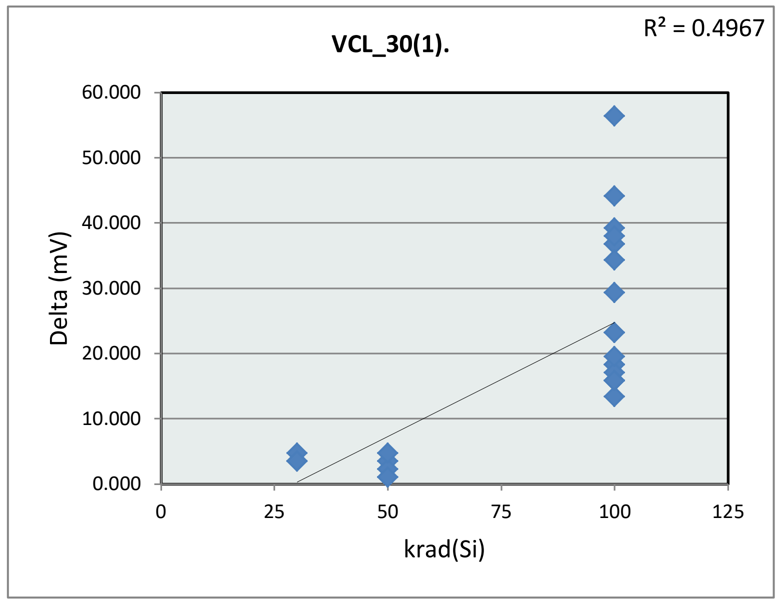


	IOFFL_15(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	15	uA	
Min Limit	-15	uA	
krad(Si)	30	50	100
LL	-15.000	-15.000	-15.000
Min	-0.012	-0.012	-0.015
Average	-0.012	-0.012	0.002
Max	-0.012	-0.012	0.004
UL	15.000	15.000	15.000

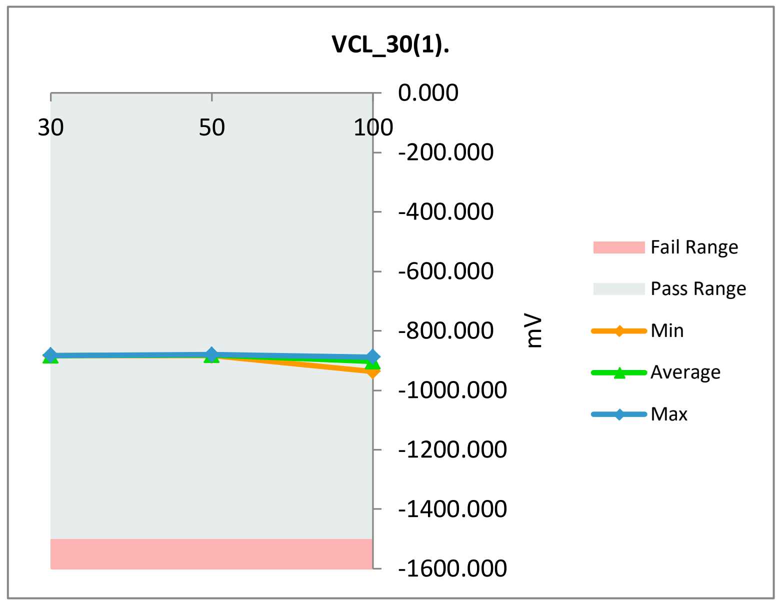


HDR TID Report T0 data
SN55LVCP22A-SP

		VCL_30(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-879.195	-883.884	4.689
30	2	-879.195	-882.656	3.461
30	3	-879.195	-882.656	3.461
30	4	-880.424	-883.884	3.460
30	5	-880.424	-883.884	3.460
50	11	-880.424	-883.884	3.460
50	12	-879.195	-880.200	1.005
50	13	-879.195	-881.428	2.233
50	14	-877.967	-882.656	4.689
50	15	-880.424	-881.428	1.004
100	22	-880.151	-916.871	36.720
100	23	-877.695	-914.415	36.720
100	24	-878.923	-908.274	29.351
100	25	-880.151	-903.361	23.210
100	26	-877.695	-893.536	15.841
100	27	-877.695	-895.992	18.297
100	28	-877.695	-895.992	18.297
100	29	-876.467	-894.764	18.297
100	30	-877.695	-894.764	17.069
100	31	-878.923	-894.764	15.841
100	32	-878.923	-894.764	15.841
100	33	-875.239	-888.623	13.384
100	34	-880.151	-936.521	56.370
100	35	-880.151	-924.240	44.089
100	36	-880.151	-914.415	34.264
100	37	-880.151	-919.327	39.176
100	38	-874.011	-911.958	37.947
100	39	-878.923	-902.133	23.210
100	40	-880.151	-895.992	15.841
100	41	-880.151	-899.677	19.526
100	42	-878.923	-894.764	15.841
100	43	-880.151	-895.992	15.841
100	44	-880.151	-895.992	15.841
	Max	-874.011	-880.200	56.370
	Average	-878.968	-897.385	18.416
	Min	-880.424	-936.521	1.004
	Std Dev	1.547	14.152	14.183

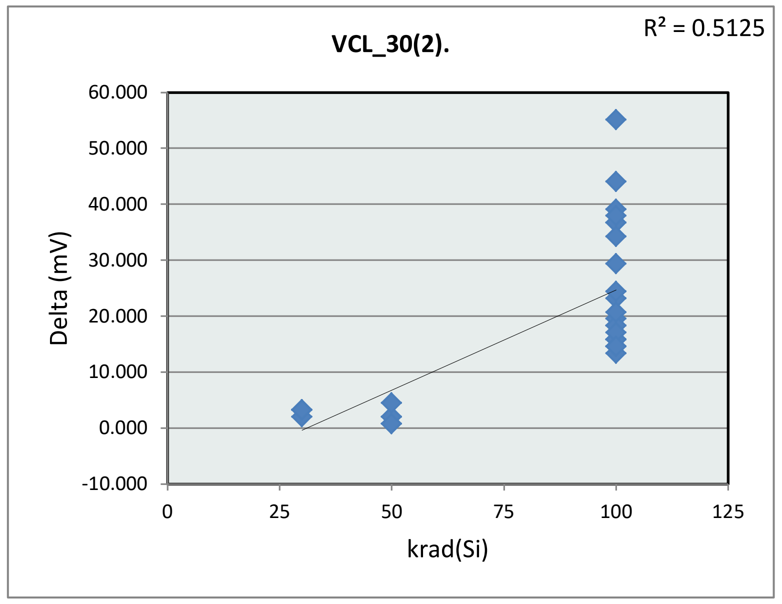


	VCL_30(1).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-1500	mV	
krad(Si)	30	50	100
LL	-1500.000	-1500.000	-1500.000
Min	-883.884	-883.884	-936.521
Average	-883.393	-881.919	-903.788
Max	-882.656	-880.200	-888.623
UL			

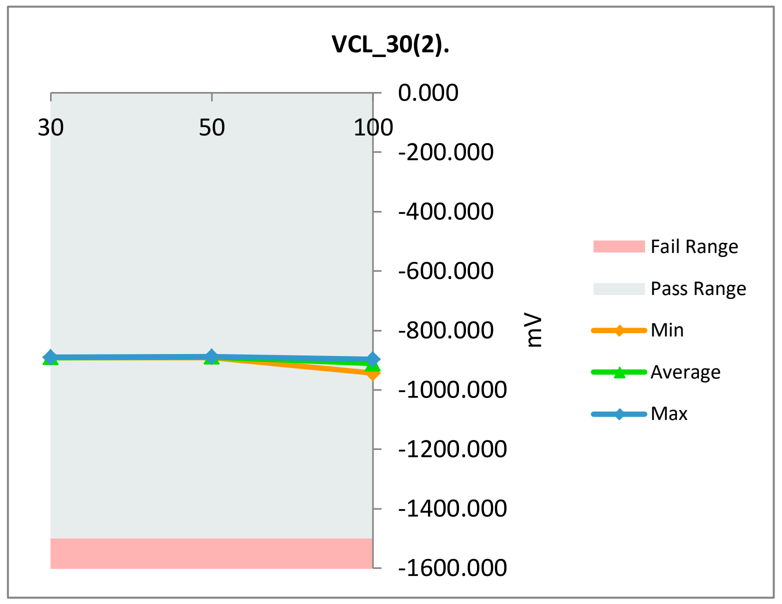


HDR TID Report T0 data
SN55LVCP22A-SP

		VCL_30(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-889.031	-891.020	1.989
30	2	-886.577	-889.793	3.216
30	3	-887.804	-891.020	3.216
30	4	-887.804	-891.020	3.216
30	5	-889.031	-892.246	3.215
50	11	-889.031	-891.020	1.989
50	12	-887.804	-888.566	0.762
50	13	-887.804	-889.793	1.989
50	14	-885.350	-889.793	4.443
50	15	-887.804	-888.566	0.762
100	22	-887.501	-924.167	36.666
100	23	-885.048	-921.714	36.666
100	24	-887.501	-916.807	29.306
100	25	-887.501	-910.673	23.172
100	26	-886.275	-902.086	15.811
100	27	-886.275	-904.540	18.265
100	28	-885.048	-904.540	19.492
100	29	-885.048	-903.313	18.265
100	30	-885.048	-900.859	15.811
100	31	-887.501	-903.313	15.812
100	32	-887.501	-902.086	14.585
100	33	-883.821	-897.179	13.358
100	34	-888.728	-943.795	55.067
100	35	-888.728	-932.755	44.027
100	36	-887.501	-921.714	34.213
100	37	-888.728	-927.848	39.120
100	38	-882.594	-920.487	37.893
100	39	-886.275	-910.673	24.398
100	40	-887.501	-903.313	15.812
100	41	-887.501	-908.220	20.719
100	42	-886.275	-903.313	17.038
100	43	-887.501	-902.086	14.585
100	44	-887.501	-902.086	14.585
	Max	-882.594	-888.566	55.067
	Average	-886.998	-905.164	18.166
	Min	-889.031	-943.795	0.762
	Std Dev	1.550	14.229	14.313

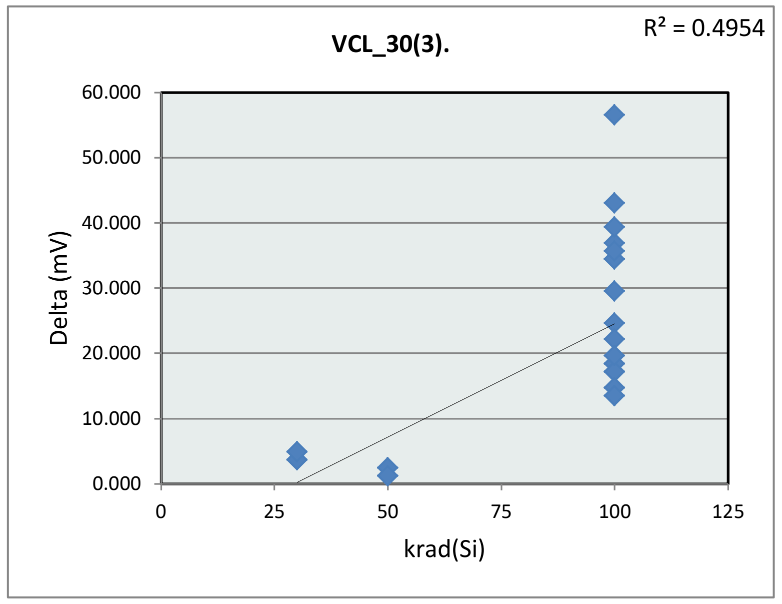


	VCL_30(2).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-1500	mV	
krad(Si)	30	50	100
LL	-1500.000	-1500.000	-1500.000
Min	-892.246	-891.020	-943.795
Average	-891.020	-889.548	-911.633
Max	-889.793	-888.566	-897.179
UL			

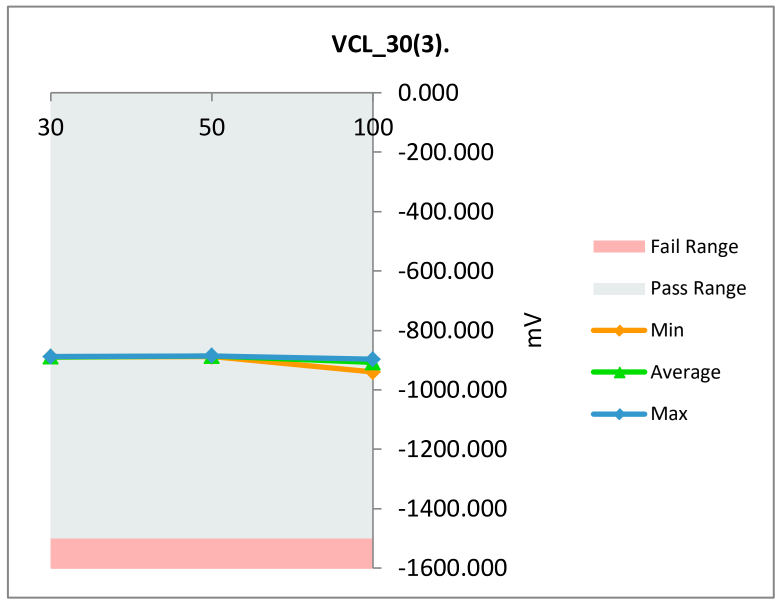


HDR TID Report T0 data
SN55LVCP22A-SP

		VCL_30(3).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	-884.749	-888.397	3.648
30	2	-884.749	-888.397	3.648
30	3	-884.749	-888.397	3.648
30	4	-884.749	-889.626	4.877
30	5	-884.749	-889.626	4.877
50	11	-885.978	-888.397	2.419
50	12	-884.749	-885.937	1.188
50	13	-884.749	-885.937	1.188
50	14	-884.749	-887.167	2.418
50	15	-885.978	-887.167	1.189
100	22	-885.266	-919.672	34.406
100	23	-882.808	-919.672	36.864
100	24	-882.808	-912.298	29.490
100	25	-884.037	-908.611	24.574
100	26	-881.579	-898.778	17.199
100	27	-882.808	-901.237	18.429
100	28	-881.579	-900.007	18.428
100	29	-881.579	-900.007	18.428
100	30	-882.808	-900.007	17.199
100	31	-884.037	-898.778	14.741
100	32	-882.808	-897.549	14.741
100	33	-881.579	-898.778	17.199
100	34	-884.037	-940.566	56.529
100	35	-885.266	-928.276	43.010
100	36	-884.037	-918.443	34.406
100	37	-884.037	-923.360	39.323
100	38	-881.579	-917.214	35.635
100	39	-884.037	-906.153	22.116
100	40	-884.037	-901.237	17.200
100	41	-884.037	-903.695	19.658
100	42	-884.037	-898.778	14.741
100	43	-885.266	-898.778	13.512
100	44	-885.266	-898.778	13.512
	Max	-881.579	-885.937	56.529
	Average	-883.918	-902.113	18.195
	Min	-885.978	-940.566	1.188
	Std Dev	1.310	13.724	14.070

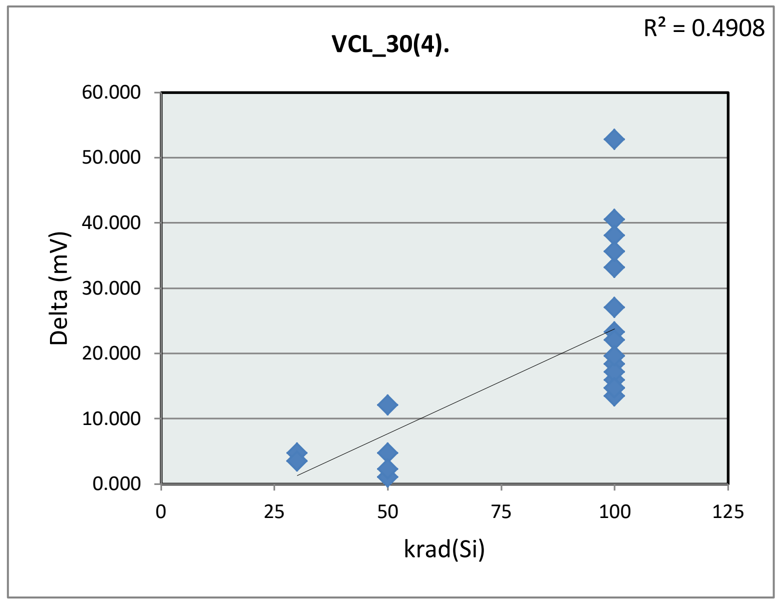


	VCL_30(3).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-1500	mV	
krad(Si)	30	50	100
LL	-1500.000	-1500.000	-1500.000
Min	-889.626	-888.397	-940.566
Average	-888.889	-886.921	-908.290
Max	-888.397	-885.937	-897.549
UL			

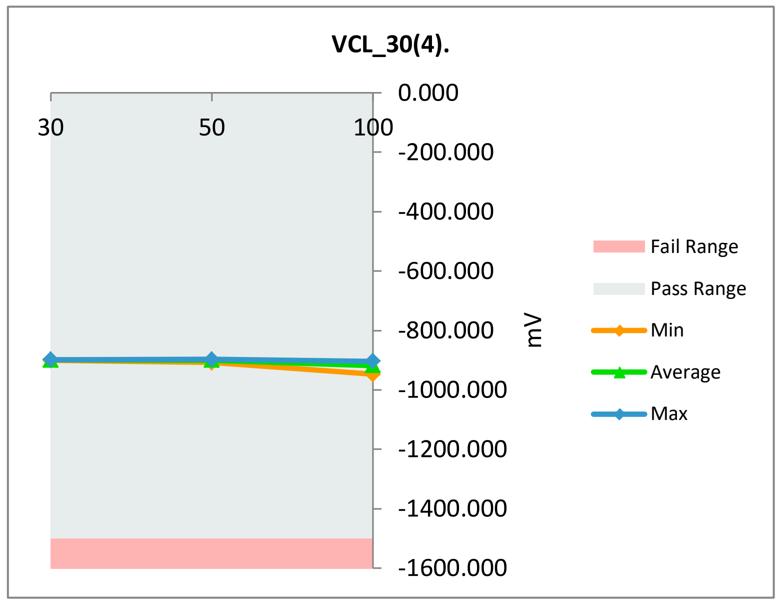


HDR TID Report T0 data
SN55LVCP22A-SP

		VCL_30(4).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-894.781	-898.263	3.482
30	2	-896.010	-899.491	3.481
30	3	-896.010	-899.491	3.481
30	4	-896.010	-900.719	4.709
30	5	-896.010	-899.491	3.481
50	11	-896.010	-908.090	12.080
50	12	-896.010	-897.034	1.024
50	13	-896.010	-897.034	1.024
50	14	-893.553	-898.263	4.710
50	15	-896.010	-898.263	2.253
100	22	-895.326	-928.459	33.133
100	23	-892.869	-928.459	35.590
100	24	-894.098	-921.090	26.992
100	25	-895.326	-918.633	23.307
100	26	-892.869	-908.807	15.938
100	27	-892.869	-912.492	19.623
100	28	-891.641	-910.035	18.394
100	29	-891.641	-910.035	18.394
100	30	-894.098	-908.807	14.709
100	31	-894.098	-908.807	14.709
100	32	-894.098	-907.579	13.481
100	33	-890.413	-903.894	13.481
100	34	-895.326	-948.112	52.786
100	35	-896.554	-937.057	40.503
100	36	-894.098	-927.231	33.133
100	37	-894.098	-932.144	38.046
100	38	-889.185	-924.775	35.590
100	39	-895.326	-917.405	22.079
100	40	-894.098	-911.263	17.165
100	41	-894.098	-913.720	19.622
100	42	-895.326	-910.035	14.709
100	43	-895.326	-910.035	14.709
100	44	-895.326	-910.035	14.709
	Max	-889.185	-897.034	52.786
	Average	-894.379	-912.274	17.895
	Min	-896.554	-948.112	1.024
	Std Dev	1.753	12.739	13.088

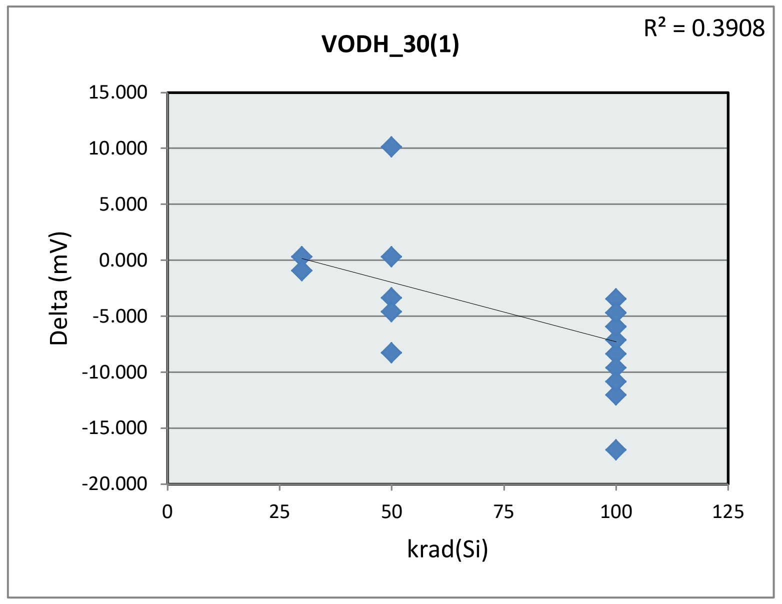


	VCL_30(4).		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-1500	mV	
krad(Si)	30	50	100
LL	-1500.000	-1500.000	-1500.000
Min	-900.719	-908.090	-948.112
Average	-899.491	-899.737	-917.779
Max	-898.263	-897.034	-903.894
UL			

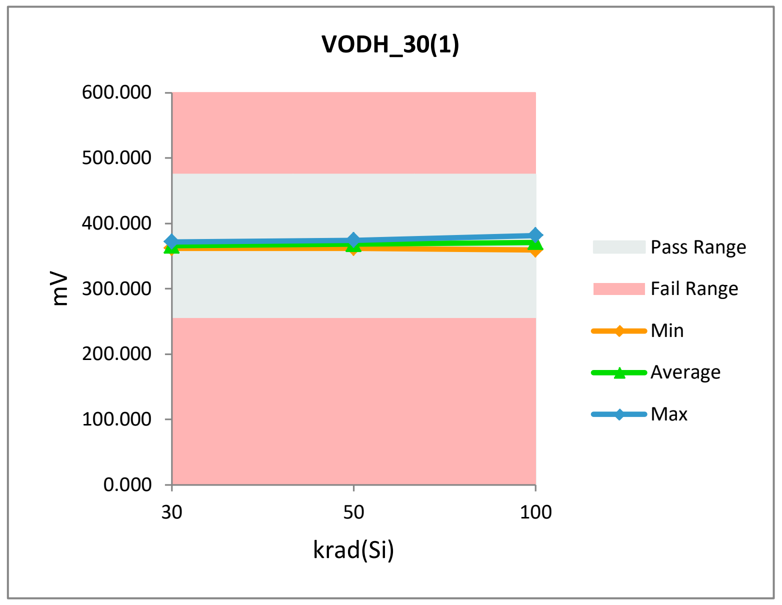


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		475	475	
Min Limit		255	255	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	365.917	366.849	-0.932
30	2	364.689	365.621	-0.932
30	3	372.056	371.761	0.295
30	4	362.235	361.941	0.294
30	5	361.006	361.938	-0.932
50	11	365.918	374.213	-8.295
50	12	362.238	365.623	-3.385
50	13	372.056	361.945	10.111
50	14	367.144	366.849	0.295
50	15	367.145	371.761	-4.616
100	22	361.033	369.421	-8.388
100	23	370.851	381.691	-10.840
100	24	367.168	374.324	-7.156
100	25	363.488	371.874	-8.386
100	26	367.169	373.100	-5.931
100	27	364.716	370.650	-5.934
100	28	365.941	373.095	-7.154
100	29	363.489	368.195	-4.706
100	30	361.032	365.733	-4.701
100	31	361.033	364.507	-3.474
100	32	364.714	370.643	-5.929
100	33	365.942	370.644	-4.702
100	34	363.487	380.466	-16.979
100	35	361.034	373.105	-12.071
100	36	368.397	378.010	-9.613
100	37	362.260	374.326	-12.066
100	38	367.167	378.003	-10.836
100	39	357.350	363.280	-5.930
100	40	358.579	362.059	-3.480
100	41	359.807	365.742	-5.935
100	42	354.898	359.604	-4.706
100	43	365.942	370.645	-4.703
100	44	365.942	370.645	-4.703
	Max	372.056	381.691	10.111
	Average	364.298	369.644	-5.346
	Min	354.898	359.604	-16.979
	Std Dev	3.934	5.605	4.829

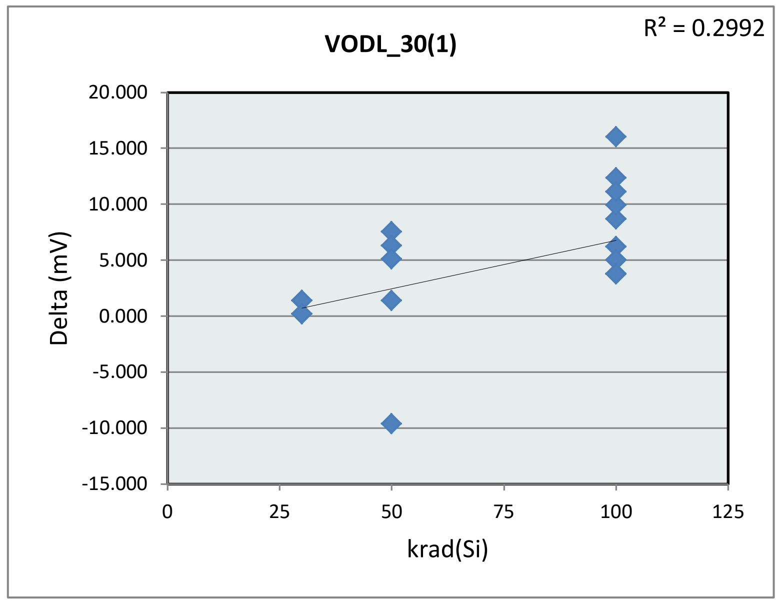


	VODH_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	361.938	361.945	359.604
Average	365.622	368.078	370.859
Max	371.761	374.213	381.691
UL	475.000	475.000	475.000

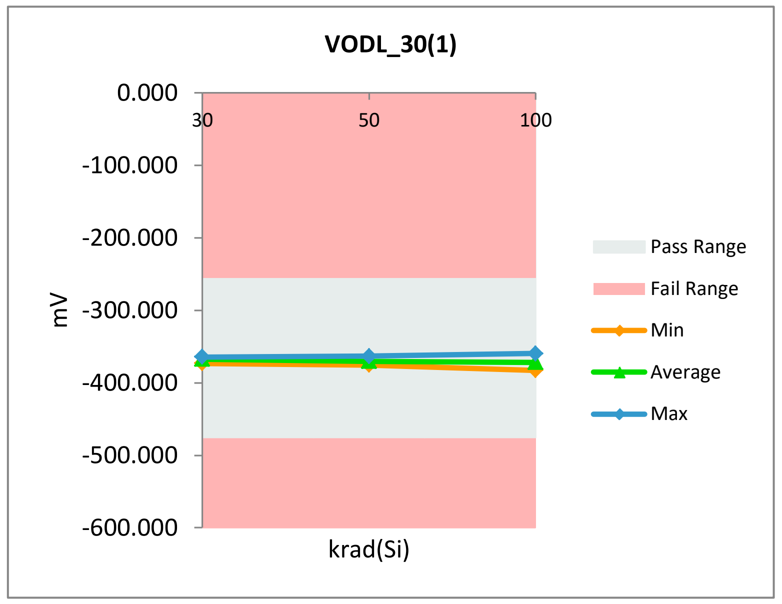


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-255	-255	
Min Limit		-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-365.566	-365.747	0.181
30	2	-366.794	-368.203	1.409
30	3	-371.700	-373.107	1.407
30	4	-363.111	-364.520	1.409
30	5	-364.340	-364.523	0.183
50	11	-368.020	-375.563	7.543
50	12	-363.108	-369.428	6.320
50	13	-372.927	-363.289	-9.638
50	14	-368.021	-369.429	1.408
50	15	-369.247	-374.334	5.087
100	22	-363.028	-371.700	8.672
100	23	-370.392	-380.290	9.898
100	24	-366.711	-375.387	8.676
100	25	-366.710	-372.929	6.219
100	26	-369.164	-374.157	4.993
100	27	-369.164	-372.926	3.762
100	28	-370.393	-375.388	4.995
100	29	-363.028	-369.245	6.217
100	30	-361.802	-366.799	4.997
100	31	-361.802	-366.798	4.996
100	32	-365.484	-369.251	3.767
100	33	-366.710	-370.477	3.767
100	34	-366.710	-382.741	16.031
100	35	-360.573	-372.925	12.352
100	36	-369.165	-379.063	9.898
100	37	-364.257	-375.385	11.128
100	38	-367.939	-379.071	11.132
100	39	-359.348	-364.344	4.996
100	40	-360.574	-364.338	3.764
100	41	-360.573	-365.563	4.990
100	42	-355.665	-359.432	3.767
100	43	-365.483	-369.250	3.767
100	44	-365.483	-369.250	3.767
	Max	-355.665	-359.432	16.031
	Average	-365.545	-370.753	5.208
	Min	-372.927	-382.741	-9.638
	Std Dev	3.886	5.453	4.537

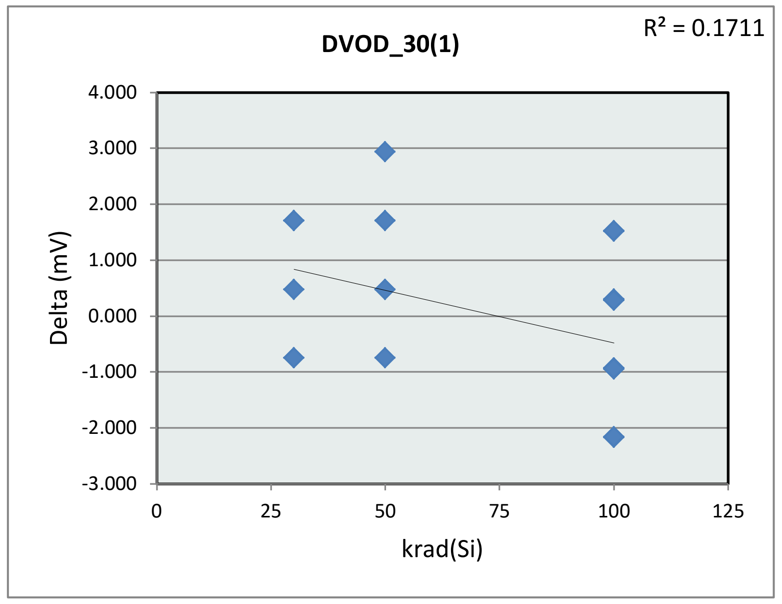


	VODL_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-373.107	-375.563	-382.741
Average	-367.220	-370.409	-371.596
Max	-364.520	-363.289	-359.432
UL	-255.000	-255.000	-255.000

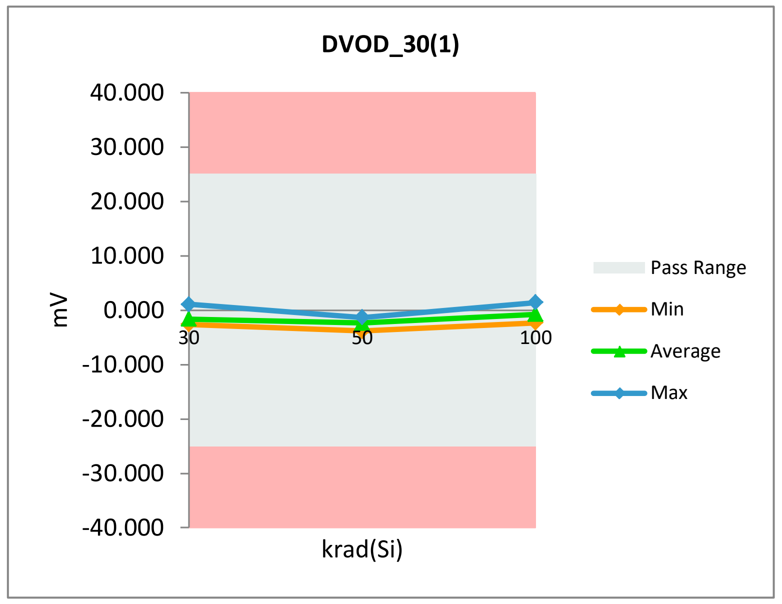


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	0.351	1.102	-0.751
30	2	-2.105	-2.582	0.477
30	3	0.356	-1.346	1.702
30	4	-0.875	-2.579	1.704
30	5	-3.334	-2.584	-0.750
50	11	-2.102	-1.350	-0.752
50	12	-0.870	-3.806	2.936
50	13	-0.871	-1.345	0.474
50	14	-0.878	-2.579	1.701
50	15	-2.102	-2.573	0.471
100	22	-1.995	-2.279	0.284
100	23	0.459	1.401	-0.942
100	24	0.457	-1.063	1.520
100	25	-3.223	-1.055	-2.168
100	26	-1.995	-1.057	-0.938
100	27	-4.448	-2.276	-2.172
100	28	-4.452	-2.293	-2.159
100	29	0.461	-1.050	1.511
100	30	-0.770	-1.066	0.296
100	31	-0.769	-2.290	1.521
100	32	-0.769	1.392	-2.161
100	33	-0.768	0.167	-0.935
100	34	-3.223	-2.275	-0.948
100	35	0.460	0.179	0.281
100	36	-0.768	-1.052	0.284
100	37	-1.997	-1.059	-0.938
100	38	-0.772	-1.068	0.296
100	39	-1.998	-1.064	-0.934
100	40	-1.994	-2.280	0.286
100	41	-0.766	0.180	-0.946
100	42	-0.767	0.172	-0.939
100	43	0.459	1.395	-0.936
100	44	0.459	1.395	-0.936
	Max	0.461	1.401	2.936
	Average	-1.247	-1.109	-0.138
	Min	-4.452	-3.806	-2.172
	Std Dev	1.399	1.404	1.299



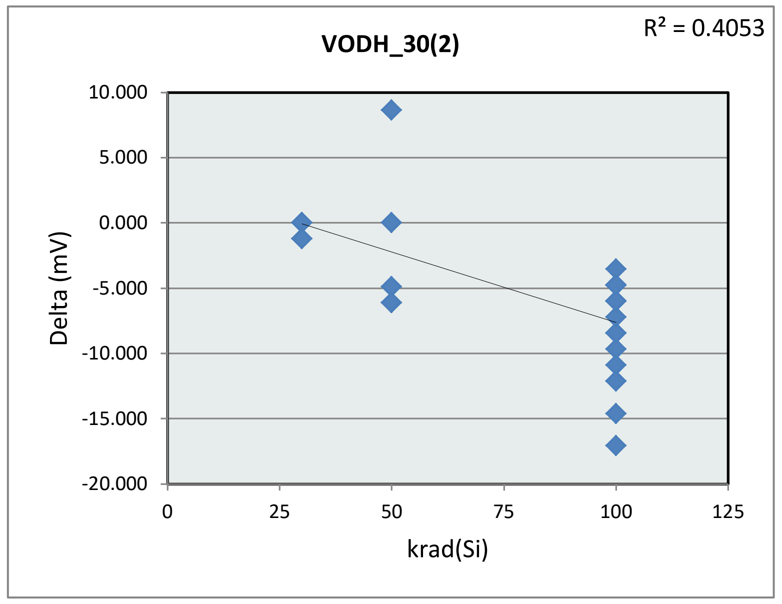
	DVOD_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-2.584	-3.806	-2.293
Average	-1.598	-2.331	-0.737
Max	1.102	-1.345	1.401
UL	25.000	25.000	25.000



HDR TID Report T0 data
SN55LVCP22A-SP

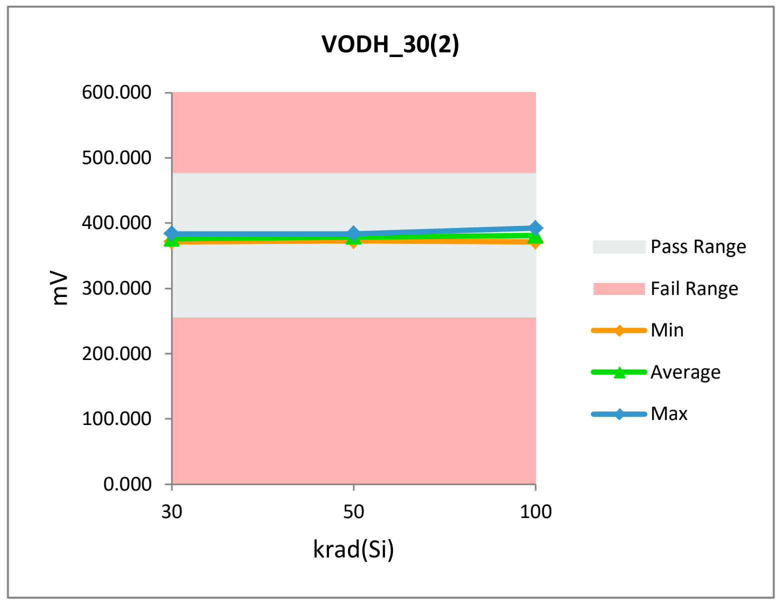
	VODH_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	475	475
Min Limit	255	255

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	375.145	375.129	0.016
30	2	376.378	376.356	0.022
30	3	382.513	383.720	-1.207
30	4	371.465	371.447	0.018
30	5	372.690	373.901	-1.211
50	11	377.605	383.720	-6.115
50	12	372.692	377.584	-4.892
50	13	381.290	372.674	8.616
50	14	378.836	378.811	0.025
50	15	375.156	381.266	-6.110
100	22	370.188	379.877	-9.689
100	23	380.010	388.468	-8.458
100	24	372.644	381.104	-8.460
100	25	373.867	382.331	-8.464
100	26	378.781	383.558	-4.777
100	27	375.096	381.104	-6.008
100	28	377.552	382.331	-4.779
100	29	371.413	377.422	-6.009
100	30	368.962	372.514	-3.552
100	31	372.639	378.649	-6.010
100	32	375.097	379.876	-4.779
100	33	372.645	377.423	-4.778
100	34	375.101	392.150	-17.049
100	35	372.634	387.238	-14.604
100	36	376.330	387.241	-10.911
100	37	371.418	383.559	-12.141
100	38	373.872	386.014	-12.142
100	39	368.952	376.193	-7.241
100	40	366.499	371.285	-4.786
100	41	372.641	378.649	-6.008
100	42	366.506	372.513	-6.007
100	43	373.871	378.649	-4.778
100	44	373.871	378.649	-4.778
	Max	382.513	392.150	8.616
	Average	374.071	379.740	-5.668
	Min	366.499	371.285	-17.049
	Std Dev	3.796	5.176	4.833



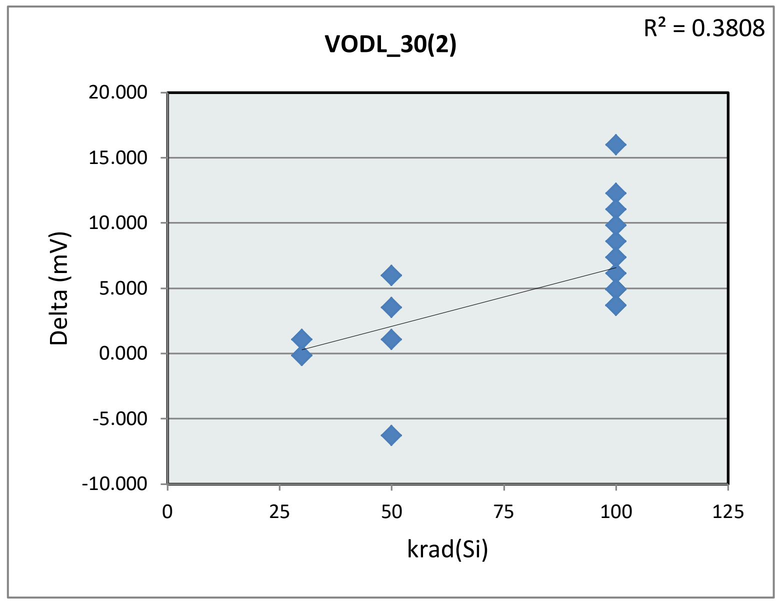
	VODH_30(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	475	mV
Min Limit	255	mV

krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	371.447	372.674	371.285
Average	376.111	378.811	380.730
Max	383.720	383.720	392.150
UL	475.000	475.000	475.000

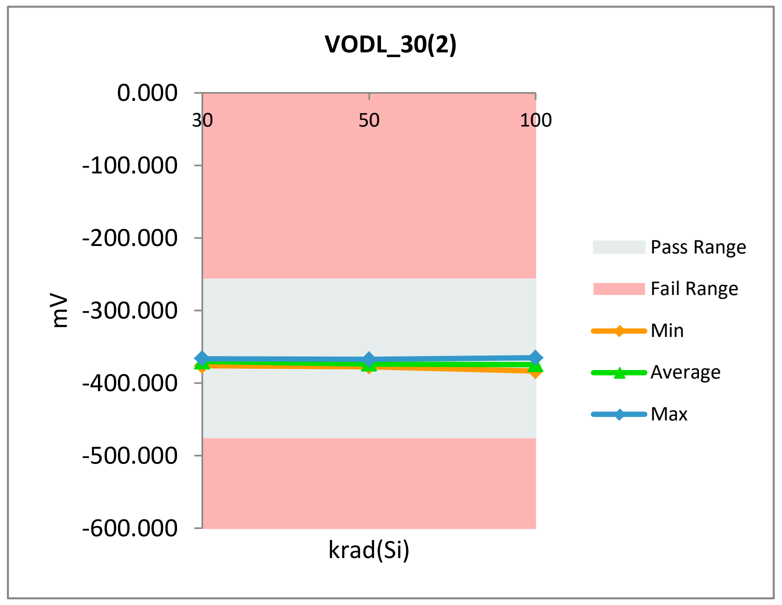


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-368.809	-368.648	-0.161
30	2	-372.486	-372.329	-0.157
30	3	-374.945	-376.012	1.067
30	4	-366.351	-366.193	-0.158
30	5	-366.354	-367.420	1.066
50	11	-373.714	-377.239	3.525
50	12	-367.579	-373.557	5.978
50	13	-373.712	-367.420	-6.292
50	14	-374.938	-376.011	1.073
50	15	-367.571	-373.557	5.986
100	22	-363.774	-371.140	7.366
100	23	-373.590	-382.183	8.593
100	24	-368.682	-376.049	7.367
100	25	-368.687	-374.823	6.136
100	26	-372.364	-376.049	3.685
100	27	-369.912	-374.822	4.910
100	28	-373.593	-377.277	3.684
100	29	-366.231	-371.141	4.910
100	30	-361.317	-366.232	4.915
100	31	-366.233	-369.915	3.682
100	32	-371.139	-376.050	4.911
100	33	-371.135	-376.049	4.914
100	34	-367.453	-383.410	15.957
100	35	-367.465	-379.732	12.267
100	36	-371.134	-380.956	9.822
100	37	-367.453	-378.502	11.049
100	38	-371.136	-380.957	9.821
100	39	-363.782	-368.688	4.906
100	40	-361.326	-366.234	4.908
100	41	-367.458	-372.368	4.910
100	42	-360.092	-365.005	4.913
100	43	-366.228	-369.914	3.686
100	44	-366.228	-369.914	3.686
	Max	-360.092	-365.005	15.957
	Average	-368.572	-373.509	4.937
	Min	-374.945	-383.410	-6.292
	Std Dev	3.969	5.072	4.137

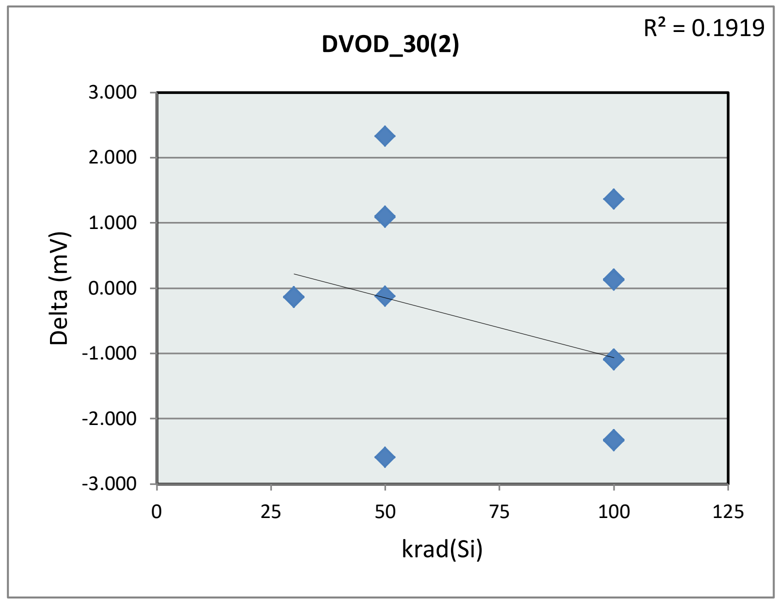


	VODL_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-376.012	-377.239	-383.410
Average	-370.120	-373.557	-374.235
Max	-366.193	-367.420	-365.005
UL	-255.000	-255.000	-255.000

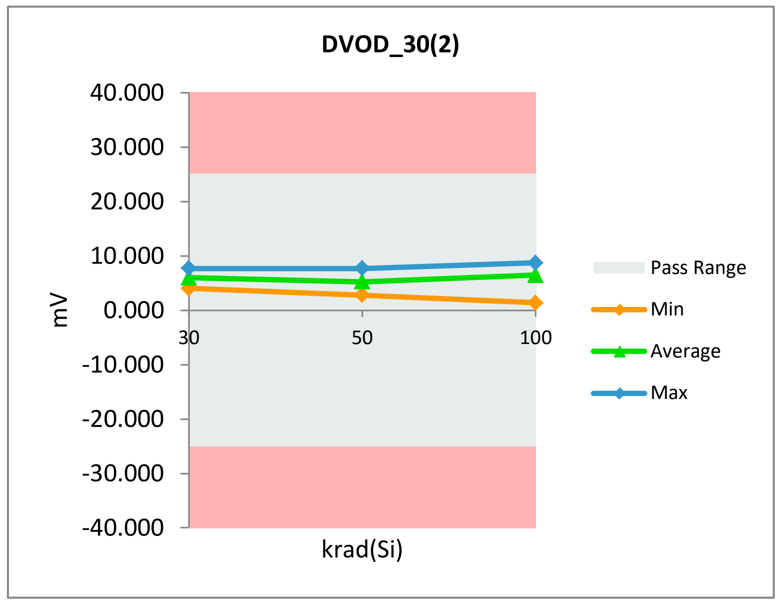


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	6.336	6.481	-0.145
30	2	3.892	4.027	-0.135
30	3	7.569	7.709	-0.140
30	4	5.114	5.254	-0.140
30	5	6.336	6.481	-0.145
50	11	3.891	6.481	-2.590
50	12	5.113	4.027	1.086
50	13	7.578	5.254	2.324
50	14	3.898	2.800	1.098
50	15	7.585	7.709	-0.124
100	22	6.414	8.737	-2.323
100	23	6.421	6.285	0.136
100	24	3.961	5.055	-1.094
100	25	5.180	7.508	-2.328
100	26	6.417	7.509	-1.092
100	27	5.184	6.281	-1.097
100	28	3.959	5.054	-1.095
100	29	5.182	6.280	-1.098
100	30	7.645	6.282	1.363
100	31	6.406	8.734	-2.328
100	32	3.958	3.827	0.131
100	33	1.510	1.374	0.136
100	34	7.648	8.740	-1.092
100	35	5.169	7.506	-2.337
100	36	5.196	6.285	-1.089
100	37	3.965	5.057	-1.092
100	38	2.736	5.057	-2.321
100	39	5.170	7.505	-2.335
100	40	5.173	5.051	0.122
100	41	5.184	6.280	-1.096
100	42	6.414	7.508	-1.094
100	43	7.642	8.736	-1.094
100	44	7.642	8.736	-1.094
	Max	7.648	8.740	2.324
	Average	5.500	6.231	-0.731
	Min	1.510	1.374	-2.590
	Std Dev	1.569	1.801	1.196

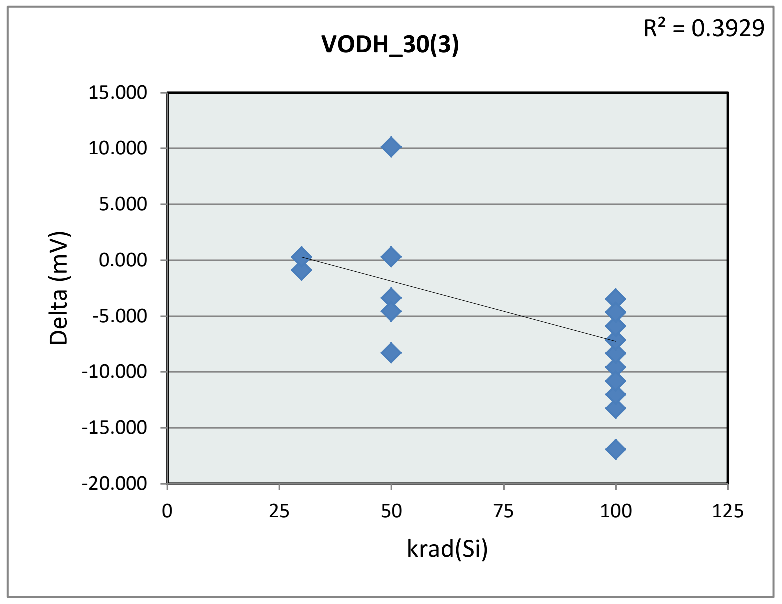


	DVOD_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	4.027	2.800	1.374
Average	5.990	5.254	6.495
Max	7.709	7.709	8.740
UL	25.000	25.000	25.000

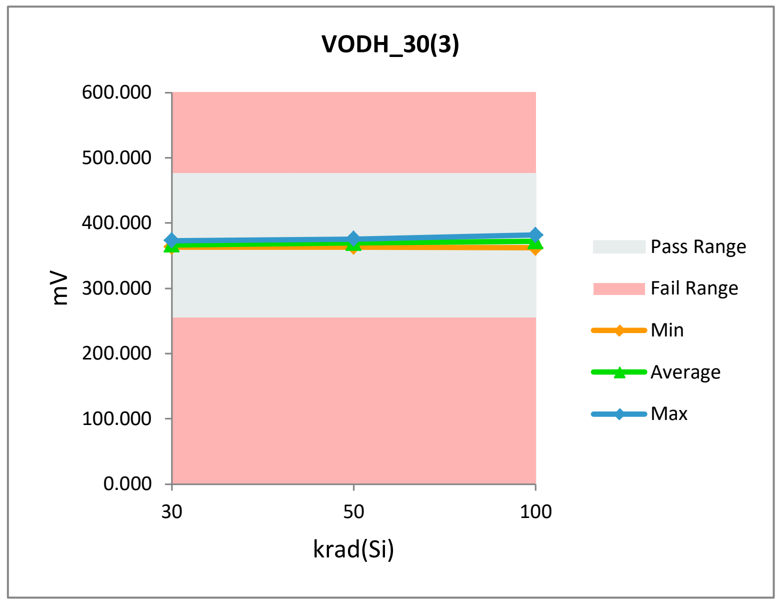


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_30(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		475	475	
Min Limit		255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	367.142	366.847	0.295
30	2	365.914	366.845	-0.931
30	3	372.054	372.985	-0.931
30	4	363.461	363.166	0.295
30	5	363.459	363.163	0.296
50	11	367.143	375.438	-8.295
50	12	363.464	366.847	-3.383
50	13	373.281	363.170	10.111
50	14	368.369	368.074	0.295
50	15	368.370	372.985	-4.615
100	22	362.260	370.645	-8.385
100	23	372.077	381.687	-9.610
100	24	368.395	376.774	-8.379
100	25	364.714	371.870	-7.156
100	26	369.623	374.324	-4.701
100	27	365.942	370.646	-4.704
100	28	368.395	373.092	-4.697
100	29	363.488	369.419	-5.931
100	30	362.259	366.956	-4.697
100	31	361.032	365.731	-4.699
100	32	367.168	370.640	-3.472
100	33	367.168	370.640	-3.472
100	34	363.487	380.462	-16.975
100	35	361.033	374.328	-13.295
100	36	369.623	380.460	-10.837
100	37	364.713	376.776	-12.063
100	38	368.394	379.226	-10.832
100	39	358.577	365.731	-7.154
100	40	358.578	364.509	-5.931
100	41	361.034	366.966	-5.932
100	42	356.124	362.055	-5.931
100	43	367.168	371.868	-4.700
100	44	367.168	371.868	-4.700
	Max	373.281	381.687	10.111
	Average	365.487	370.794	-5.307
	Min	356.124	362.055	-16.975
	Std Dev	4.053	5.421	4.926

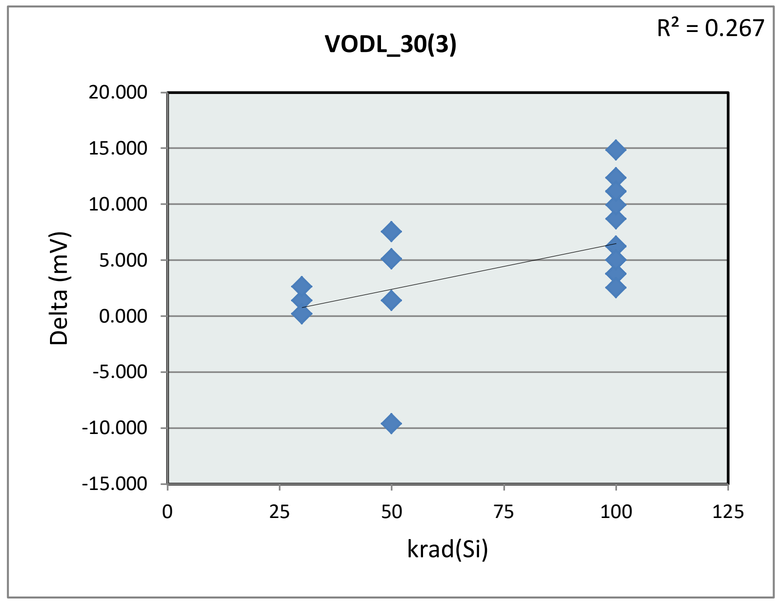


	VODH_30(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	363.163	363.170	362.055
Average	366.601	369.303	372.029
Max	372.985	375.438	381.687
UL	475.000	475.000	475.000

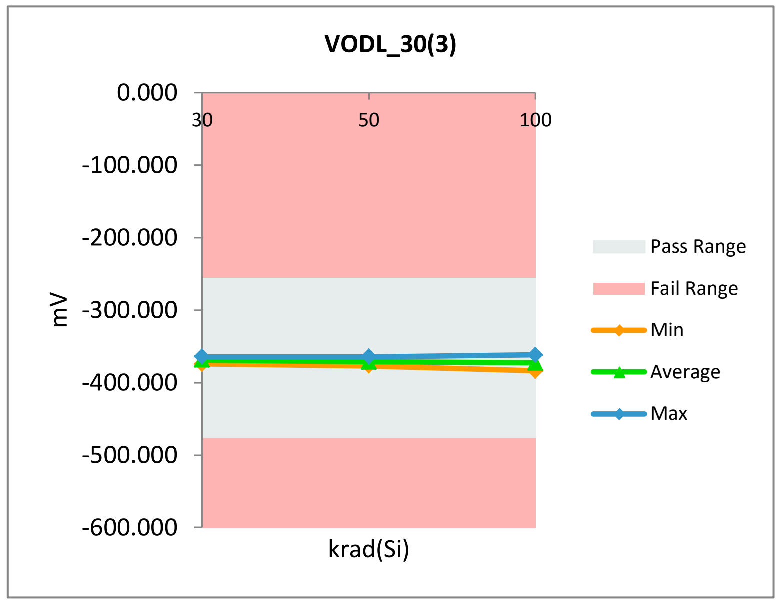


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-366.795	-368.204	1.409
30	2	-368.023	-369.433	1.410
30	3	-374.157	-374.337	0.180
30	4	-364.340	-364.522	0.182
30	5	-364.342	-366.979	2.637
50	11	-369.249	-376.793	7.544
50	12	-364.337	-369.431	5.094
50	13	-374.157	-364.519	-9.638
50	14	-369.251	-370.658	1.407
50	15	-370.476	-375.564	5.088
100	22	-364.256	-372.931	8.675
100	23	-370.393	-381.521	11.128
100	24	-369.166	-375.391	6.225
100	25	-369.165	-372.932	3.767
100	26	-370.393	-375.387	4.994
100	27	-369.165	-374.157	4.992
100	28	-371.621	-376.618	4.997
100	29	-364.256	-369.248	4.992
100	30	-364.258	-368.030	3.772
100	31	-364.257	-368.028	3.771
100	32	-366.711	-370.481	3.770
100	33	-367.938	-371.708	3.770
100	34	-369.166	-383.973	14.807
100	35	-361.802	-374.156	12.354
100	36	-370.393	-380.294	9.901
100	37	-365.484	-377.843	12.359
100	38	-369.167	-380.302	11.135
100	39	-359.349	-365.575	6.226
100	40	-360.574	-365.569	4.995
100	41	-361.801	-365.566	3.765
100	42	-356.893	-361.889	4.996
100	43	-367.938	-370.480	2.542
100	44	-367.938	-370.480	2.542
	Max	-356.893	-361.889	14.807
	Average	-366.885	-371.909	5.024
	Min	-374.157	-383.973	-9.638
	Std Dev	4.020	5.423	4.517

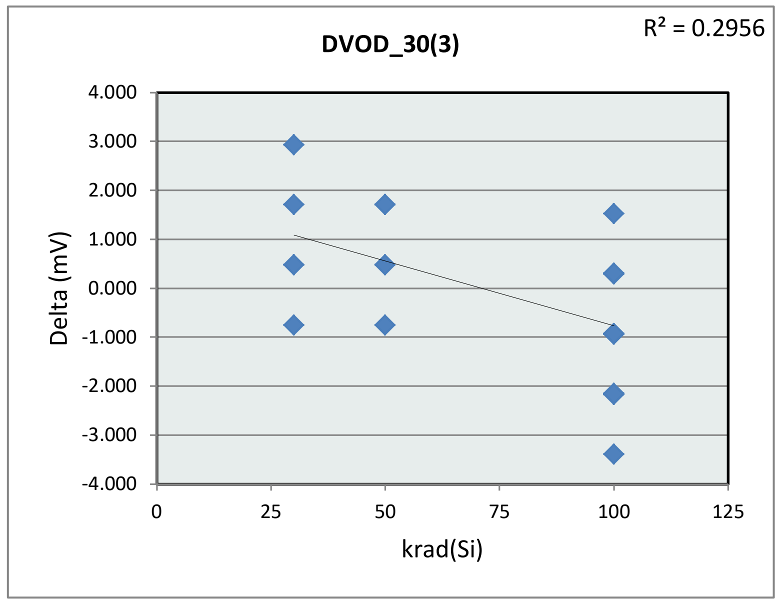


	VODL_30(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-374.337	-376.793	-383.973
Average	-368.695	-371.393	-372.720
Max	-364.522	-364.519	-361.889
UL	-255.000	-255.000	-255.000



HDR TID Report T0 data
SN55LVCP22A-SP

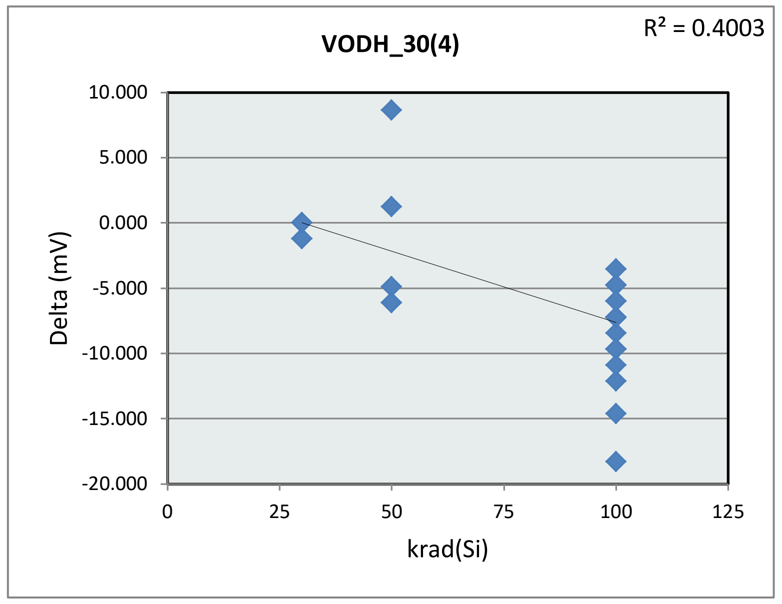
		DVOD_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	0.347	-1.357	1.704
30	2	-2.109	-2.587	0.478
30	3	-2.103	-1.352	-0.751
30	4	-0.879	-1.356	0.477
30	5	-0.884	-3.816	2.932
50	11	-2.106	-1.355	-0.751
50	12	-0.873	-2.583	1.710
50	13	-0.875	-1.349	0.474
50	14	-0.881	-2.585	1.704
50	15	-2.106	-2.579	0.473
100	22	-1.997	-2.287	0.290
100	23	1.685	0.166	1.519
100	24	-0.772	1.383	-2.155
100	25	-4.452	-1.062	-3.390
100	26	-0.770	-1.063	0.293
100	27	-3.223	-3.511	0.288
100	28	-3.226	-3.526	0.300
100	29	-0.768	0.171	-0.939
100	30	-1.999	-1.073	-0.926
100	31	-3.225	-2.297	-0.928
100	32	0.457	0.158	0.298
100	33	-0.770	-1.068	0.298
100	34	-5.679	-3.511	-2.168
100	35	-0.769	0.172	-0.940
100	36	-0.770	0.167	-0.937
100	37	-0.771	-1.066	0.295
100	38	-0.773	-1.076	0.303
100	39	-0.772	0.156	-0.928
100	40	-1.996	-1.060	-0.936
100	41	-0.767	1.400	-2.167
100	42	-0.769	0.166	-0.934
100	43	-0.770	1.388	-2.158
100	44	-0.770	1.388	-2.158
	Max	1.685	1.400	2.932
	Average	-1.398	-1.115	-0.283
	Min	-5.679	-3.816	-3.390
	Std Dev	1.405	1.509	1.387



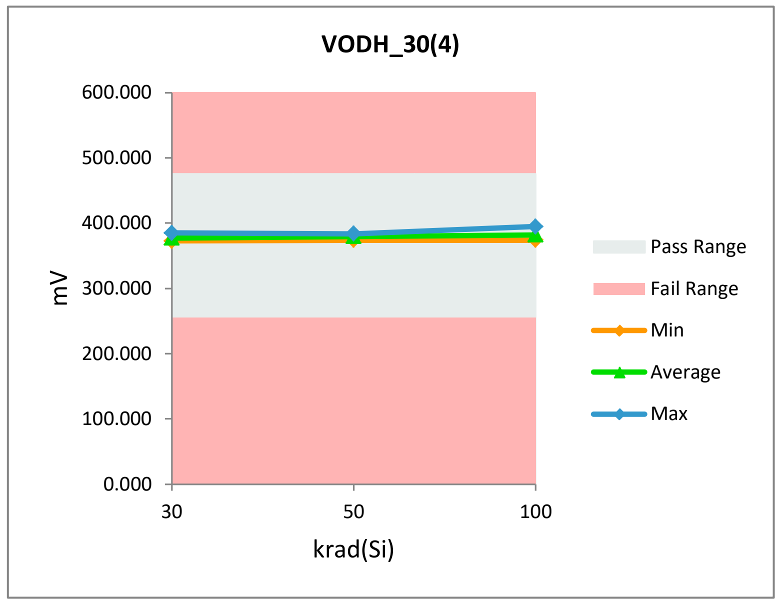
	DVOD_30(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-3.816	-2.585	-3.526
Average	-2.094	-2.090	-0.691
Max	-1.352	-1.349	1.400
UL	25.000	25.000	25.000

HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	376.370	376.356	0.014
30	2	377.603	378.811	-1.208
30	3	384.966	384.948	0.018
30	4	371.462	372.674	-1.212
30	5	373.914	373.901	0.013
50	11	378.830	383.720	-4.890
50	12	373.917	380.038	-6.121
50	13	382.515	373.901	8.614
50	14	380.061	378.811	1.250
50	15	376.381	382.493	-6.112
100	22	371.412	381.103	-9.691
100	23	381.234	390.922	-9.688
100	24	373.867	382.330	-8.463
100	25	376.318	383.557	-7.239
100	26	380.004	383.557	-3.553
100	27	376.319	381.102	-4.783
100	28	378.775	383.557	-4.782
100	29	373.864	378.648	-4.784
100	30	370.186	374.967	-4.781
100	31	373.862	379.875	-6.013
100	32	376.320	381.102	-4.782
100	33	375.097	378.649	-3.552
100	34	376.324	394.603	-18.279
100	35	373.857	388.464	-14.607
100	36	377.553	387.240	-9.687
100	37	372.642	384.786	-12.144
100	38	375.096	386.012	-10.916
100	39	368.949	376.192	-7.243
100	40	366.496	373.738	-7.242
100	41	372.638	379.875	-7.237
100	42	368.957	373.740	-4.783
100	43	373.867	379.876	-6.009
100	44	373.867	379.876	-6.009
	Max	384.966	394.603	8.614
	Average	375.258	380.892	-5.633
	Min	366.496	372.674	-18.279
	Std Dev	3.997	5.145	4.931

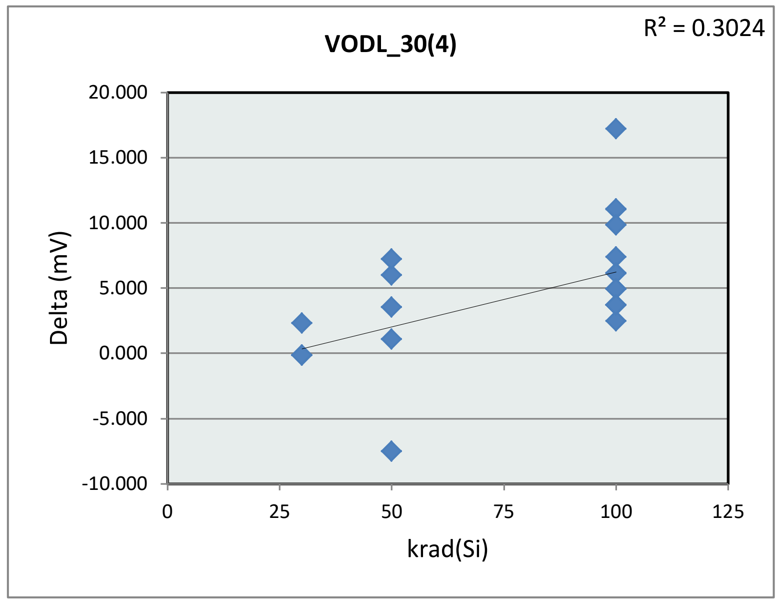


	VODH_30(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	372.674	373.901	373.738
Average	377.338	379.793	381.903
Max	384.948	383.720	394.603
UL	475.000	475.000	475.000

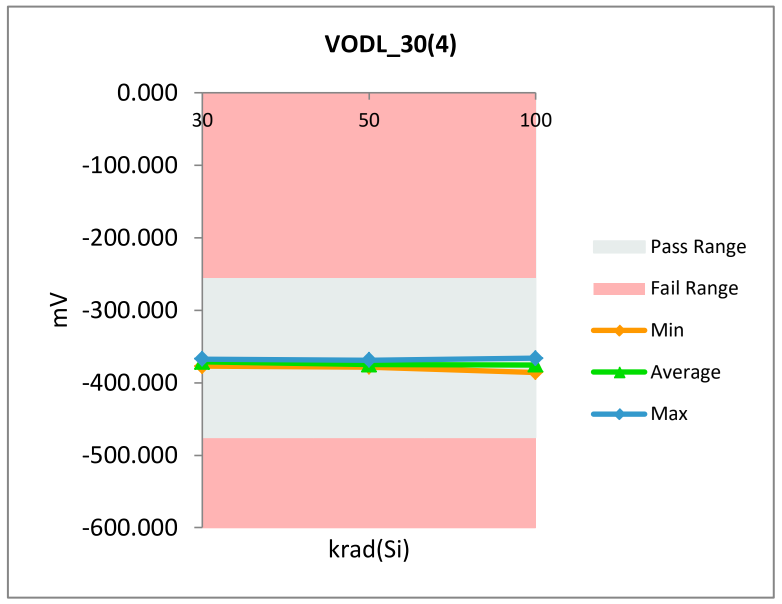


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_30(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-255	-255	
Min Limit		-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-370.039	-369.875	-0.164
30	2	-373.716	-373.557	-0.159
30	3	-377.403	-377.239	-0.164
30	4	-366.353	-368.647	2.294
30	5	-367.584	-367.420	-0.164
50	11	-374.945	-378.466	3.521
50	12	-368.809	-374.784	5.975
50	13	-376.170	-368.648	-7.522
50	14	-377.396	-378.466	1.070
50	15	-367.573	-374.784	7.211
100	22	-365.005	-372.368	7.363
100	23	-374.821	-384.639	9.818
100	24	-371.141	-377.277	6.136
100	25	-371.145	-376.051	4.906
100	26	-373.595	-378.504	4.909
100	27	-371.143	-374.823	3.680
100	28	-374.824	-378.505	3.681
100	29	-368.690	-371.142	2.452
100	30	-362.548	-366.233	3.685
100	31	-367.464	-371.143	3.679
100	32	-373.597	-377.278	3.681
100	33	-373.594	-377.277	3.683
100	34	-368.684	-385.866	17.182
100	35	-369.923	-380.960	11.037
100	36	-371.137	-380.957	9.820
100	37	-368.684	-379.730	11.046
100	38	-372.367	-382.185	9.818
100	39	-363.786	-369.916	6.130
100	40	-362.557	-367.462	4.905
100	41	-368.688	-373.596	4.908
100	42	-362.550	-366.233	3.683
100	43	-367.459	-371.142	3.683
100	44	-367.459	-371.142	3.683
	Max	-362.548	-366.233	17.182
	Average	-370.026	-374.737	4.711
	Min	-377.403	-385.866	-7.522
	Std Dev	4.201	5.290	4.376

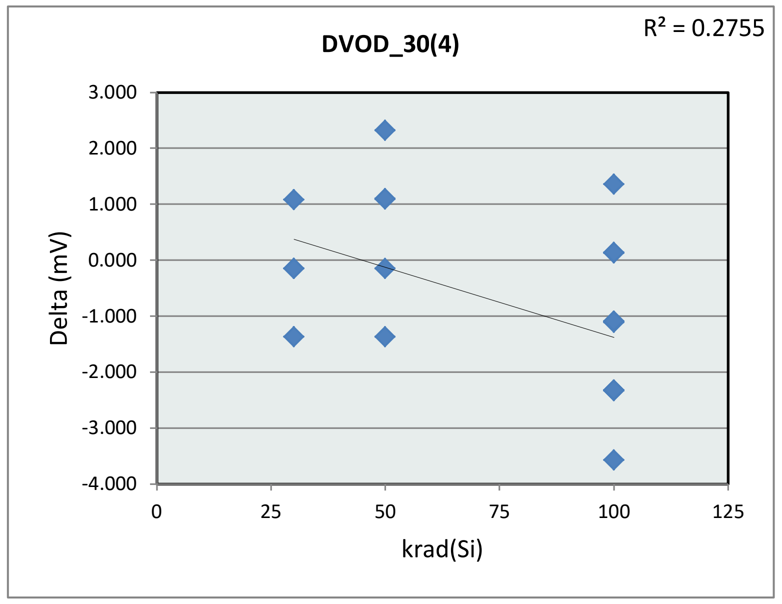


	VODL_30(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-377.239	-378.466	-385.866
Average	-371.348	-375.030	-375.410
Max	-367.420	-368.648	-366.233
UL	-255.000	-255.000	-255.000

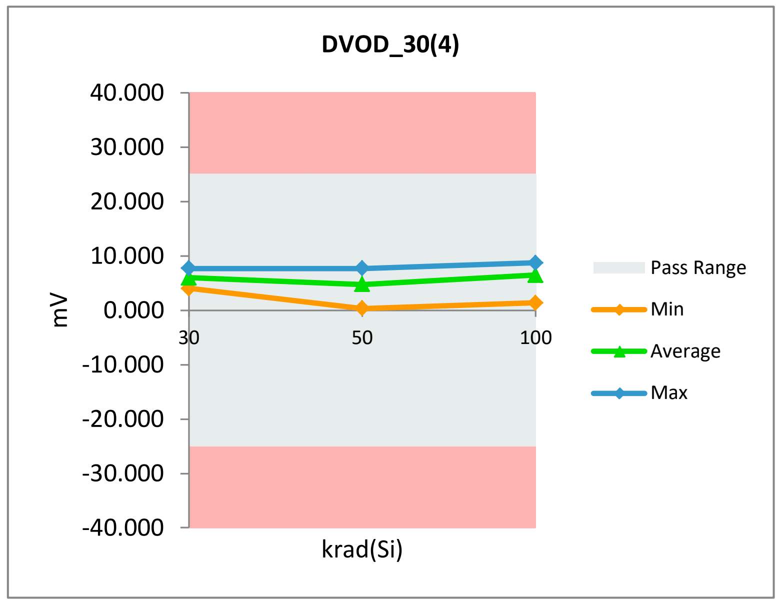


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	6.331	6.481	-0.150
30	2	3.886	5.254	-1.368
30	3	7.563	7.709	-0.146
30	4	5.109	4.027	1.082
30	5	6.330	6.481	-0.151
50	11	3.886	5.254	-1.368
50	12	5.107	5.254	-0.147
50	13	6.345	5.254	1.091
50	14	2.665	0.345	2.320
50	15	8.808	7.709	1.099
100	22	6.407	8.735	-2.328
100	23	6.413	6.283	0.130
100	24	2.726	5.053	-2.327
100	25	5.173	7.506	-2.333
100	26	6.409	5.053	1.356
100	27	5.176	6.279	-1.103
100	28	3.951	5.052	-1.101
100	29	5.174	7.506	-2.332
100	30	7.639	8.735	-1.096
100	31	6.398	8.732	-2.334
100	32	2.723	3.824	-1.101
100	33	1.503	1.372	0.131
100	34	7.640	8.738	-1.098
100	35	3.934	7.504	-3.570
100	36	6.416	6.283	0.133
100	37	3.958	5.055	-1.097
100	38	2.729	3.828	-1.099
100	39	5.163	6.276	-1.113
100	40	3.939	6.276	-2.337
100	41	3.949	6.279	-2.330
100	42	6.407	7.506	-1.099
100	43	6.408	8.734	-2.326
100	44	6.408	8.734	-2.326
	Max	8.808	8.738	2.320
	Average	5.232	6.155	-0.922
	Min	1.503	0.345	-3.570
	Std Dev	1.730	2.035	1.359

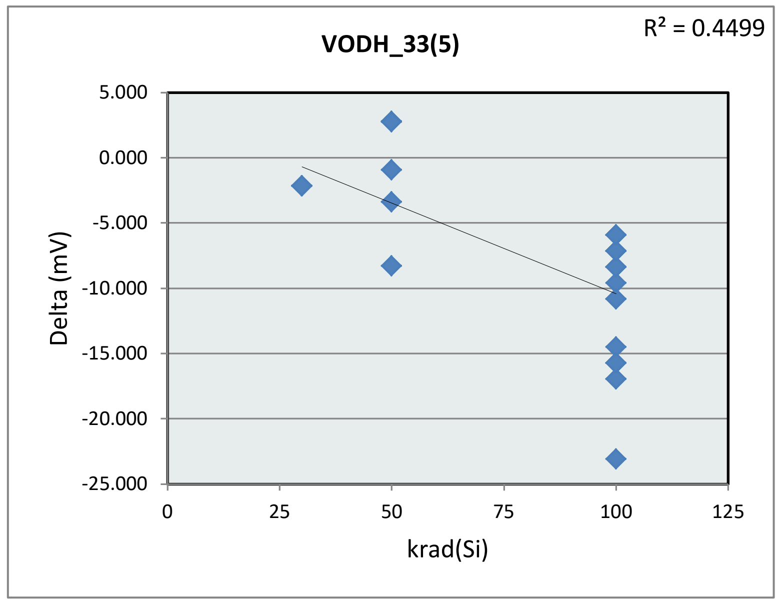


	DVOD_30(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	4.027	0.345	1.372
Average	5.990	4.763	6.493
Max	7.709	7.709	8.738
UL	25.000	25.000	25.000

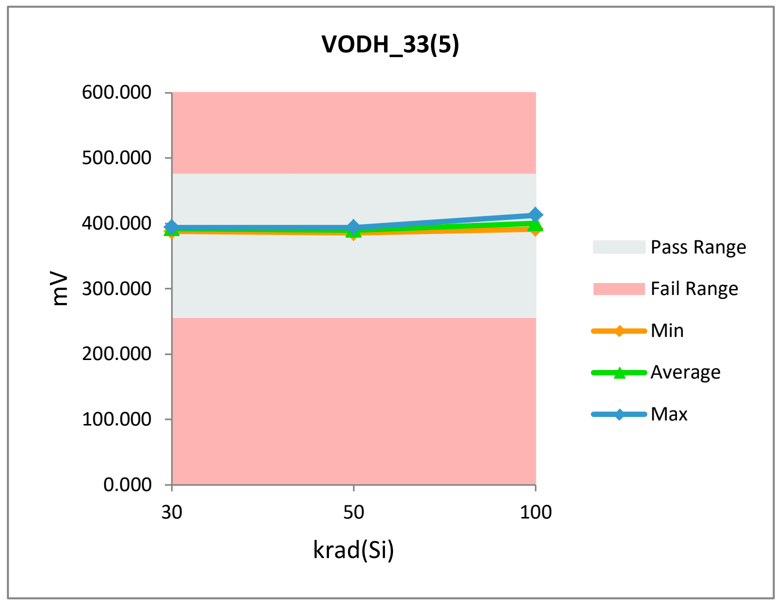


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	391.684	393.838	-2.154
30	2	385.547	387.701	-2.154
30	3	391.686	393.840	-2.154
30	4	391.685	393.839	-2.154
30	5	389.228	391.381	-2.153
50	11	385.548	393.838	-8.290
50	12	388.006	385.248	2.758
50	13	391.686	388.934	2.752
50	14	386.774	387.702	-0.928
50	15	389.230	392.613	-3.383
100	22	386.802	401.311	-14.509
100	23	389.256	406.217	-16.961
100	24	392.937	403.759	-10.822
100	25	389.256	398.856	-9.600
100	26	390.484	398.855	-8.371
100	27	388.030	395.176	-7.146
100	28	390.483	398.849	-8.366
100	29	388.031	396.407	-8.376
100	30	391.710	397.624	-5.914
100	31	390.483	396.399	-5.916
100	32	390.483	397.626	-7.143
100	33	385.575	392.718	-7.143
100	34	389.256	412.354	-23.098
100	35	390.484	407.448	-16.964
100	36	389.256	404.989	-15.733
100	37	389.256	404.988	-15.732
100	38	390.482	406.210	-15.728
100	39	388.028	398.852	-10.824
100	40	384.348	391.496	-7.148
100	41	385.576	393.953	-8.377
100	42	384.349	391.496	-7.147
100	43	392.938	398.855	-5.917
100	44	392.938	398.855	-5.917
	Max	392.938	412.354	2.758
	Average	389.137	397.037	-7.900
	Min	384.348	385.248	-23.098
	Std Dev	2.499	6.342	5.926

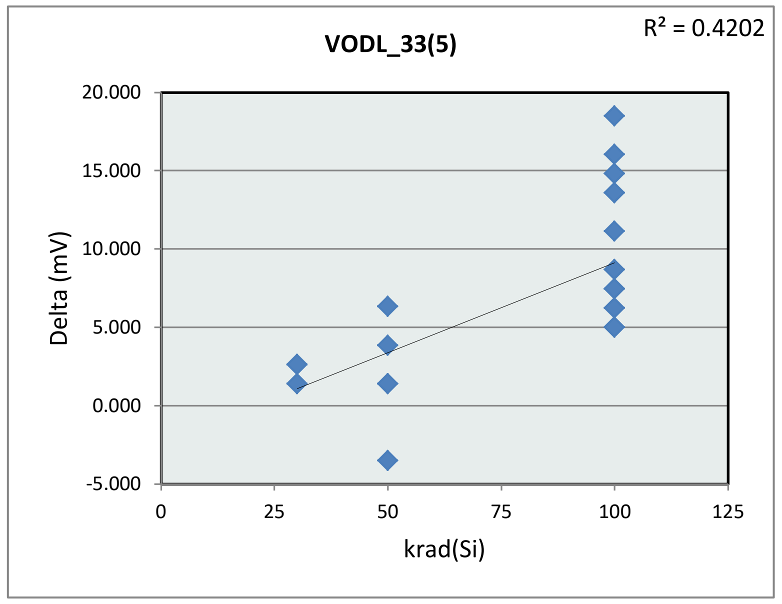


	VODH_33(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	387.701	385.248	391.496
Average	392.120	389.667	399.708
Max	393.840	393.838	412.354
UL	475.000	475.000	475.000

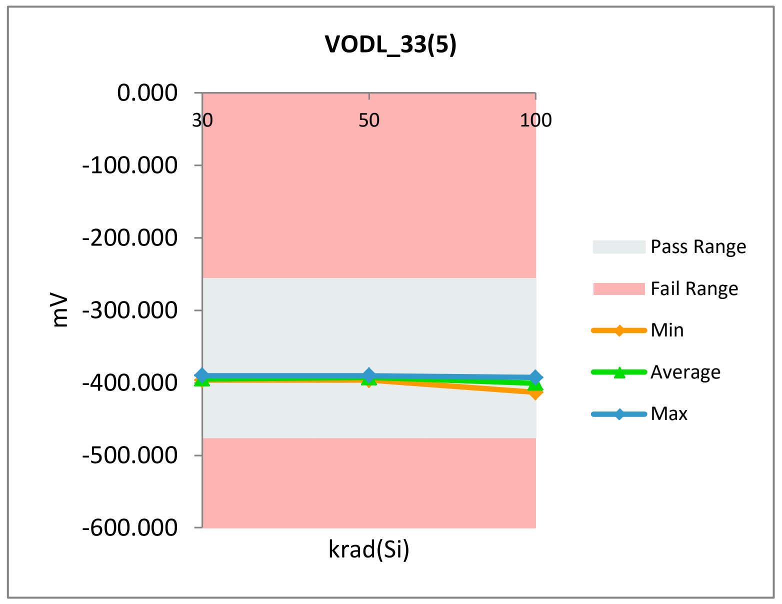


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-392.573	-395.207	2.634
30	2	-388.893	-390.300	1.407
30	3	-393.799	-396.432	2.633
30	4	-393.800	-395.206	1.406
30	5	-392.575	-395.209	2.634
50	11	-390.118	-396.434	6.316
50	12	-388.888	-390.298	1.410
50	13	-393.799	-390.294	-3.505
50	14	-388.893	-392.753	3.860
50	15	-392.573	-393.977	1.404
100	22	-390.030	-403.616	13.586
100	23	-390.030	-404.845	14.815
100	24	-393.713	-404.849	11.136
100	25	-393.712	-402.390	8.678
100	26	-392.484	-399.937	7.453
100	27	-392.484	-399.934	7.450
100	28	-393.713	-401.169	7.456
100	29	-390.029	-397.477	7.448
100	30	-392.486	-398.714	6.228
100	31	-392.485	-397.485	5.000
100	32	-392.485	-397.485	5.000
100	33	-388.803	-393.804	5.001
100	34	-394.939	-413.432	18.493
100	35	-390.029	-406.068	16.039
100	36	-391.258	-404.845	13.587
100	37	-391.258	-406.075	14.817
100	38	-392.487	-406.079	13.592
100	39	-391.258	-397.485	6.227
100	40	-388.802	-393.798	4.996
100	41	-385.120	-393.796	8.676
100	42	-386.348	-392.572	6.224
100	43	-393.712	-398.710	4.998
100	44	-393.712	-398.710	4.998
	Max	-385.120	-390.294	18.493
	Average	-391.433	-398.466	7.033
	Min	-394.939	-413.432	-3.505
	Std Dev	2.333	5.507	5.058



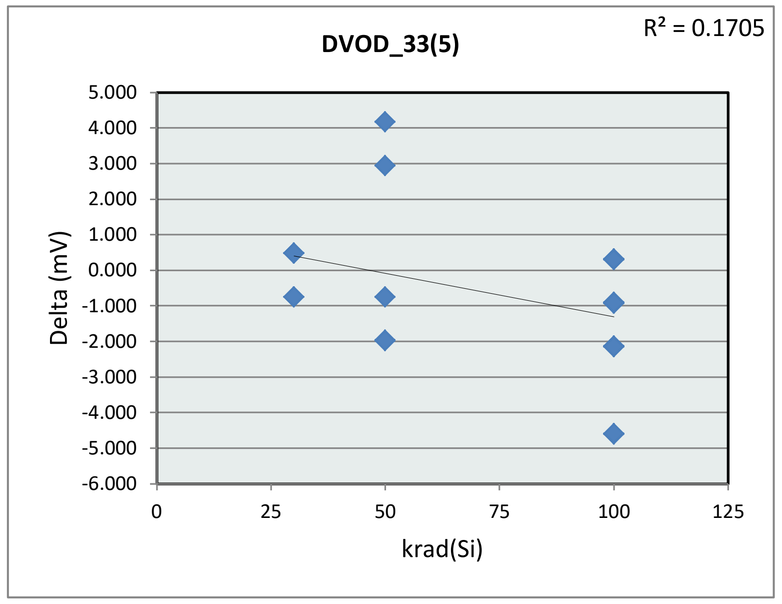
	VODL_33(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-396.432	-396.434	-413.432
Average	-394.471	-392.751	-400.577
Max	-390.300	-390.294	-392.572
UL	-255.000	-255.000	-255.000



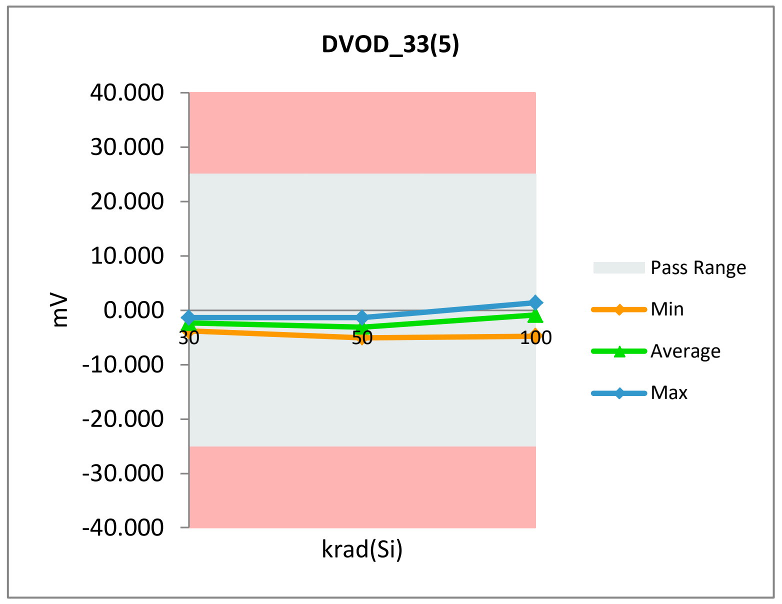
HDR TID Report T0 data
SN55LVCP22A-SP

	DVOD_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-0.889	-1.369	0.480
30	2	-3.346	-2.599	-0.747
30	3	-2.113	-2.592	0.479
30	4	-2.115	-1.367	-0.748
30	5	-3.347	-3.828	0.481
50	11	-4.570	-2.596	-1.974
50	12	-0.882	-5.050	4.168
50	13	-2.113	-1.360	-0.753
50	14	-2.118	-5.051	2.933
50	15	-3.343	-1.364	-1.979
100	22	-3.227	-2.305	-0.922
100	23	-0.774	1.371	-2.145
100	24	-0.776	-1.091	0.315
100	25	-4.455	-3.534	-0.921
100	26	-2.001	-1.082	-0.919
100	27	-4.454	-4.757	0.303
100	28	-3.230	-2.320	-0.910
100	29	-1.998	-1.070	-0.928
100	30	-0.776	-1.090	0.314
100	31	-2.001	-1.086	-0.915
100	32	-2.002	0.141	-2.143
100	33	-3.229	-1.086	-2.143
100	34	-5.683	-1.078	-4.605
100	35	0.455	1.380	-0.925
100	36	-2.002	0.144	-2.146
100	37	-2.002	-1.087	-0.915
100	38	-2.005	0.131	-2.136
100	39	-3.230	1.367	-4.597
100	40	-4.454	-2.302	-2.152
100	41	0.456	0.157	0.299
100	42	-1.999	-1.076	-0.923
100	43	-0.774	0.144	-0.918
100	44	-0.774	0.144	-0.918
	Max	0.456	1.380	4.168
	Average	-2.296	-1.429	-0.867
	Min	-5.683	-5.051	-4.605
	Std Dev	1.468	1.708	1.686

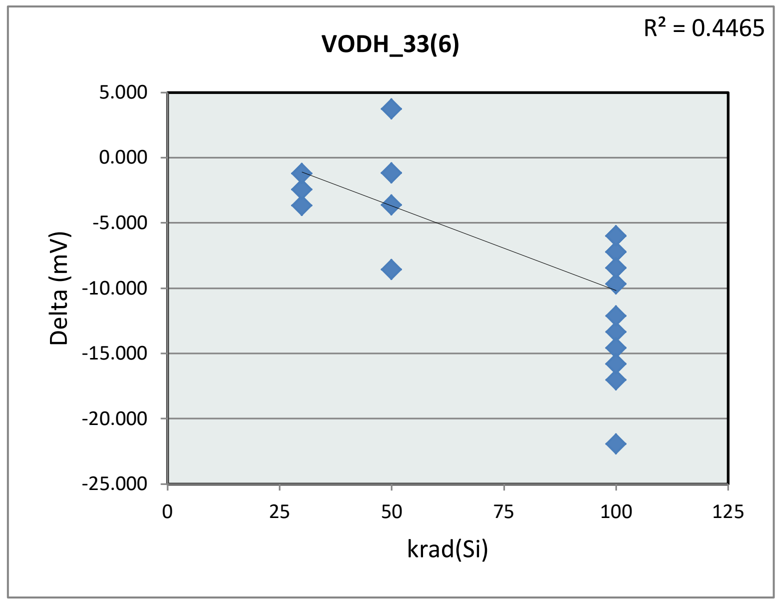


	DVOD_33(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-3.828	-5.051	-4.757
Average	-2.351	-3.084	-0.869
Max	-1.367	-1.360	1.380
UL	25.000	25.000	25.000

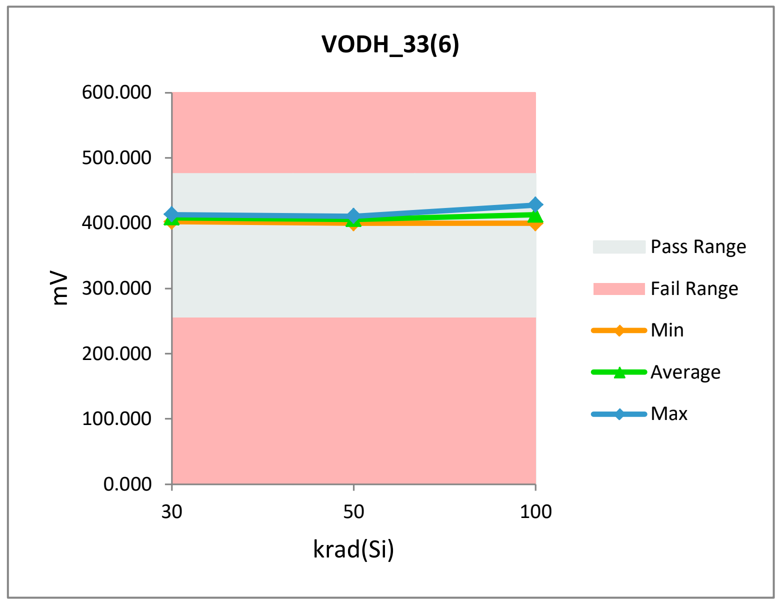


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_33(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		475	475	
Min Limit		255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	407.054	409.494	-2.440
30	2	398.466	402.130	-3.664
30	3	410.738	413.176	-2.438
30	4	405.829	407.040	-1.211
30	5	408.281	409.494	-1.213
50	11	402.147	410.722	-8.575
50	12	405.828	402.130	3.698
50	13	405.833	407.040	-1.207
50	14	398.468	399.676	-1.208
50	15	404.610	408.267	-3.657
100	22	400.859	414.233	-13.374
100	23	398.404	413.007	-14.603
100	24	402.086	414.233	-12.147
100	25	405.765	415.460	-9.695
100	26	404.541	411.779	-7.238
100	27	404.538	410.551	-6.013
100	28	403.312	411.778	-8.466
100	29	402.084	409.324	-7.240
100	30	403.316	409.325	-6.009
100	31	404.536	410.551	-6.015
100	32	402.084	409.324	-7.240
100	33	392.268	399.507	-7.239
100	34	405.771	427.733	-21.962
100	35	406.986	424.048	-17.062
100	36	403.317	417.916	-14.599
100	37	400.861	416.688	-15.827
100	38	395.951	411.780	-15.829
100	39	404.533	414.231	-9.698
100	40	400.852	408.096	-7.244
100	41	400.857	409.324	-8.467
100	42	400.859	409.325	-8.466
100	43	405.769	411.779	-6.010
100	44	405.769	411.779	-6.010
	Max	410.738	427.733	3.698
	Average	403.108	410.938	-7.829
	Min	392.268	399.507	-21.962
	Std Dev	3.708	5.802	5.540

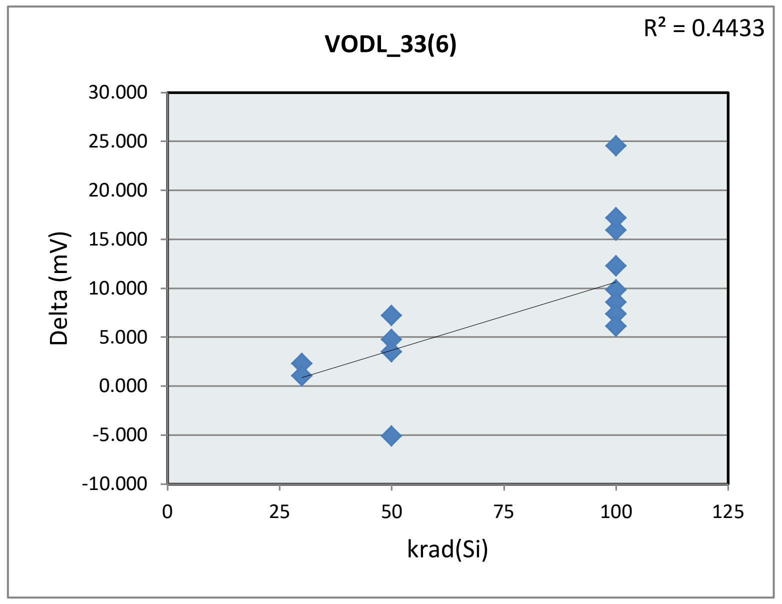


	VODH_33(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	402.130	399.676	399.507
Average	408.267	405.567	412.686
Max	413.176	410.722	427.733
UL	475.000	475.000	475.000

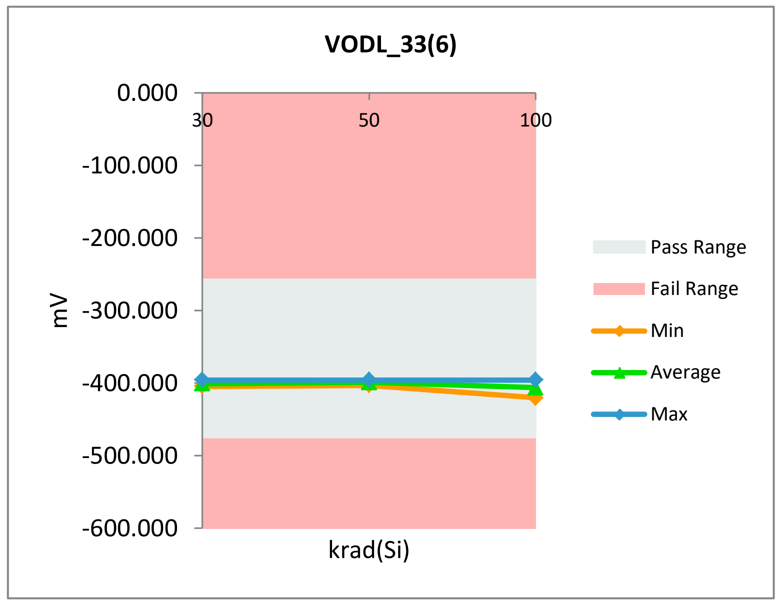


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-400.737	-401.786	1.049
30	2	-394.593	-395.649	1.056
30	3	-401.964	-404.241	2.277
30	4	-399.506	-401.786	2.280
30	5	-399.510	-400.559	1.049
50	11	-395.822	-403.014	7.192
50	12	-400.735	-395.650	-5.085
50	13	-395.820	-400.559	4.739
50	14	-394.591	-398.104	3.513
50	15	-393.360	-396.877	3.517
100	22	-393.244	-405.504	12.260
100	23	-390.789	-406.731	15.942
100	24	-395.698	-407.959	12.261
100	25	-398.157	-407.960	9.803
100	26	-396.925	-404.277	7.352
100	27	-396.928	-405.505	8.577
100	28	-398.155	-406.732	8.577
100	29	-395.701	-403.051	7.350
100	30	-394.468	-401.823	7.355
100	31	-396.930	-403.051	6.121
100	32	-396.928	-404.278	7.350
100	33	-389.561	-395.687	6.126
100	34	-395.696	-420.229	24.533
100	35	-401.845	-419.006	17.161
100	36	-396.922	-412.866	15.944
100	37	-394.468	-411.639	17.171
100	38	-390.788	-407.958	17.170
100	39	-396.933	-406.733	9.800
100	40	-395.705	-403.052	7.347
100	41	-395.700	-404.278	8.578
100	42	-394.470	-401.823	7.353
100	43	-395.698	-401.823	6.125
100	44	-395.698	-401.823	6.125
	Max	-389.561	-395.649	24.533
	Average	-396.183	-404.303	8.120
	Min	-401.964	-420.229	-5.085
	Std Dev	2.929	5.720	5.981

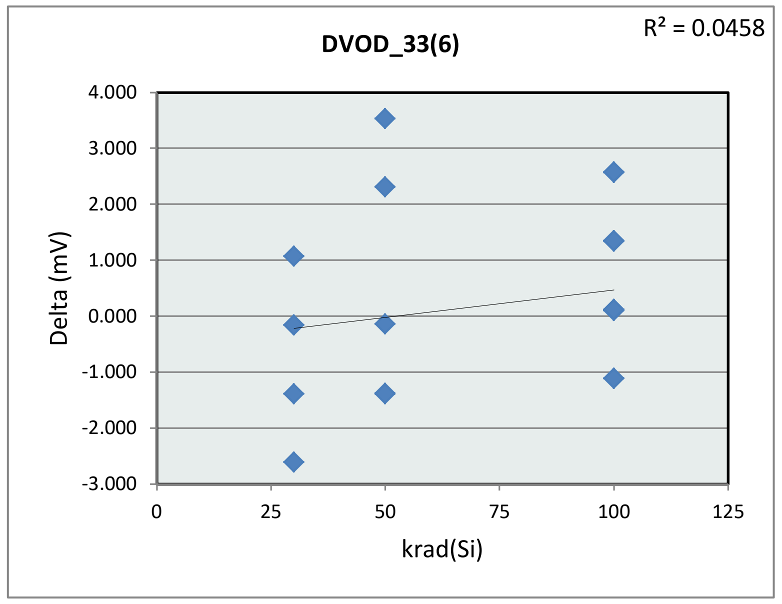


	VODL_33(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-404.241	-403.014	-420.229
Average	-400.804	-398.841	-406.252
Max	-395.649	-395.650	-395.687
UL	-255.000	-255.000	-255.000

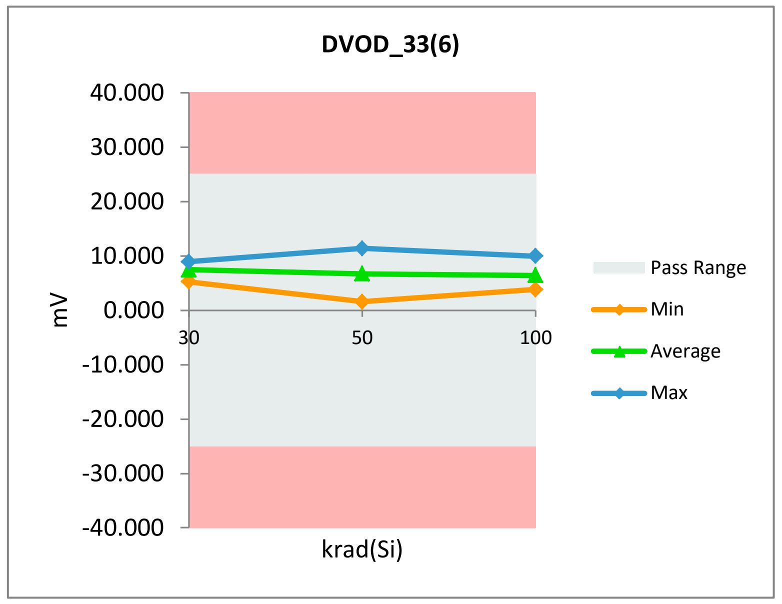


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	6.317	7.708	-1.391
30	2	3.872	6.481	-2.609
30	3	8.774	8.935	-0.161
30	4	6.323	5.253	1.070
30	5	8.771	8.935	-0.164
50	11	6.325	7.708	-1.383
50	12	5.094	6.481	-1.387
50	13	10.012	6.481	3.531
50	14	3.877	1.572	2.305
50	15	11.250	11.390	-0.140
100	22	7.615	8.729	-1.114
100	23	7.615	6.275	1.340
100	24	6.388	6.274	0.114
100	25	7.608	7.500	0.108
100	26	7.615	7.501	0.114
100	27	7.610	5.046	2.564
100	28	5.157	5.046	0.111
100	29	6.383	6.274	0.109
100	30	8.848	7.503	1.345
100	31	7.606	7.499	0.107
100	32	5.156	5.046	0.110
100	33	2.708	3.820	-1.112
100	34	10.075	7.504	2.571
100	35	5.141	5.043	0.098
100	36	6.395	5.050	1.345
100	37	6.393	5.049	1.344
100	38	5.163	3.821	1.342
100	39	7.600	7.498	0.102
100	40	5.147	5.043	0.104
100	41	5.157	5.046	0.111
100	42	6.390	7.501	-1.111
100	43	10.071	9.956	0.115
100	44	10.071	9.956	0.115
	Max	11.250	11.390	3.531
	Average	6.925	6.634	0.291
	Min	2.708	1.572	-2.609
	Std Dev	2.038	2.025	1.309



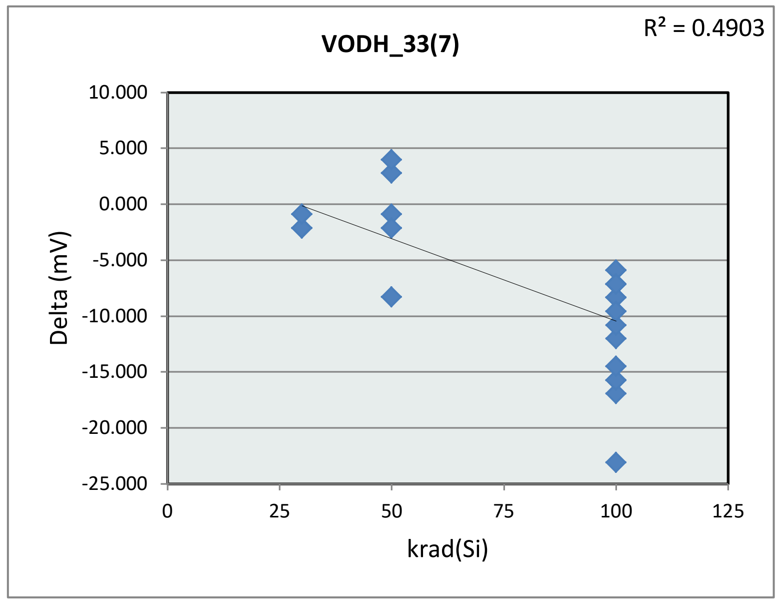
	DVOD_33(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	5.253	1.572	3.820
Average	7.462	6.726	6.434
Max	8.935	11.390	9.956
UL	25.000	25.000	25.000



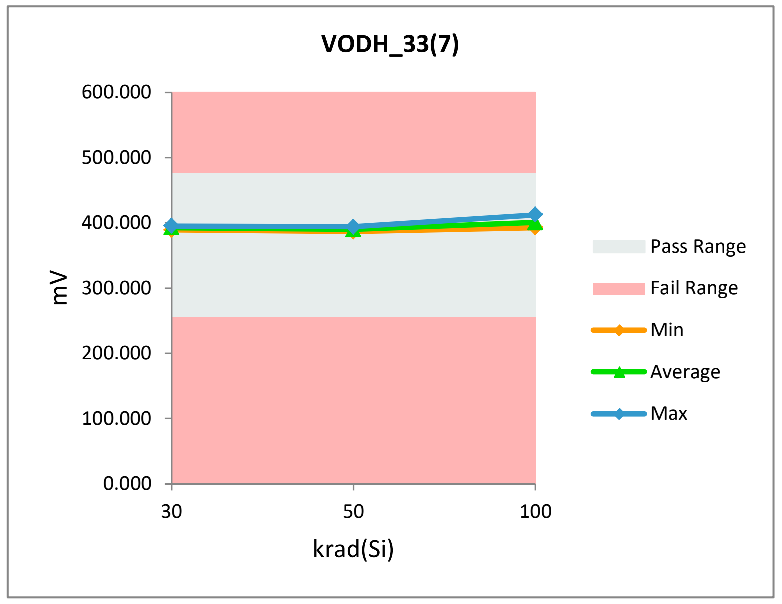
HDR TID Report T0 data
SN55LVCP22A-SP

	VODH_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	475	475
Min Limit	255	255

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	394.138	395.064	-0.926
30	2	386.773	388.926	-2.153
30	3	392.912	395.065	-2.153
30	4	391.684	393.837	-2.153
30	5	390.454	391.380	-0.926
50	11	385.547	393.836	-8.289
50	12	389.232	386.474	2.758
50	13	391.685	387.705	3.980
50	14	388.000	388.927	-0.927
50	15	390.456	392.611	-2.155
100	22	386.802	402.536	-15.734
100	23	391.710	407.441	-15.731
100	24	392.936	404.983	-12.047
100	25	389.256	400.080	-10.824
100	26	391.711	398.853	-7.142
100	27	388.029	396.401	-8.372
100	28	390.482	398.847	-8.365
100	29	390.485	396.404	-5.919
100	30	391.709	398.848	-7.139
100	31	391.710	397.624	-5.914
100	32	390.483	397.623	-7.140
100	33	386.801	392.715	-5.914
100	34	389.256	412.351	-23.095
100	35	390.484	407.446	-16.962
100	36	390.483	404.987	-14.504
100	37	389.255	404.985	-15.730
100	38	392.936	407.435	-14.499
100	39	389.255	398.850	-9.595
100	40	384.348	392.721	-8.373
100	41	385.576	395.178	-9.602
100	42	385.575	392.721	-7.146
100	43	392.938	400.079	-7.141
100	44	392.938	400.079	-7.141
	Max	394.138	412.351	3.980
	Average	389.880	397.667	-7.787
	Min	384.348	386.474	-23.095
	Std Dev	2.568	6.319	6.031

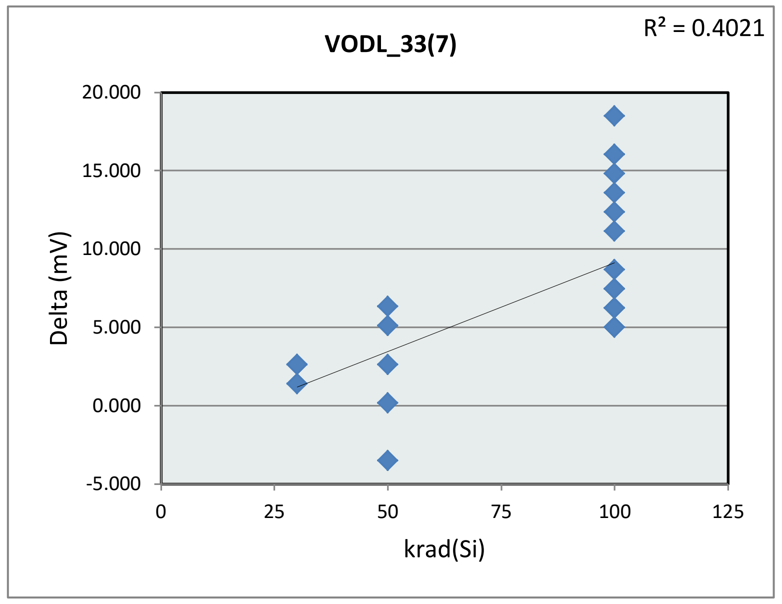


	VODH_33(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	388.926	386.474	392.715
Average	392.854	389.911	400.399
Max	395.065	393.836	412.351
UL	475.000	475.000	475.000

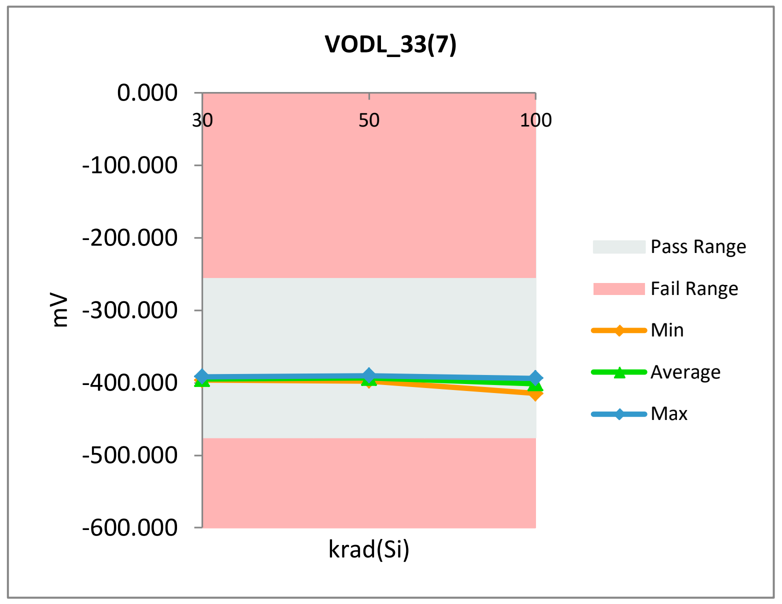


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-392.575	-395.208	2.633
30	2	-388.894	-391.529	2.635
30	3	-393.800	-396.434	2.634
30	4	-395.029	-396.435	1.406
30	5	-393.804	-395.211	1.407
50	11	-391.347	-397.663	6.316
50	12	-390.116	-390.299	0.183
50	13	-393.800	-390.296	-3.504
50	14	-388.894	-393.982	5.088
50	15	-392.574	-395.207	2.633
100	22	-391.258	-403.618	12.360
100	23	-390.031	-406.075	16.044
100	24	-393.714	-404.852	11.138
100	25	-393.712	-402.392	8.680
100	26	-393.712	-399.939	6.227
100	27	-393.712	-401.163	7.451
100	28	-394.941	-402.398	7.457
100	29	-391.257	-397.480	6.223
100	30	-393.713	-398.717	5.004
100	31	-392.486	-398.714	6.228
100	32	-391.258	-398.714	7.456
100	33	-388.804	-393.806	5.002
100	34	-396.167	-414.662	18.495
100	35	-391.257	-407.297	16.040
100	36	-392.486	-406.075	13.589
100	37	-392.486	-407.304	14.818
100	38	-392.487	-407.308	14.821
100	39	-391.259	-398.714	7.455
100	40	-390.030	-395.027	4.997
100	41	-387.575	-393.798	6.223
100	42	-387.576	-393.801	6.225
100	43	-393.713	-398.713	5.000
100	44	-393.713	-398.713	5.000
	Max	-387.575	-390.296	18.495
	Average	-392.066	-399.138	7.072
	Min	-396.167	-414.662	-3.504
	Std Dev	2.166	5.662	5.103

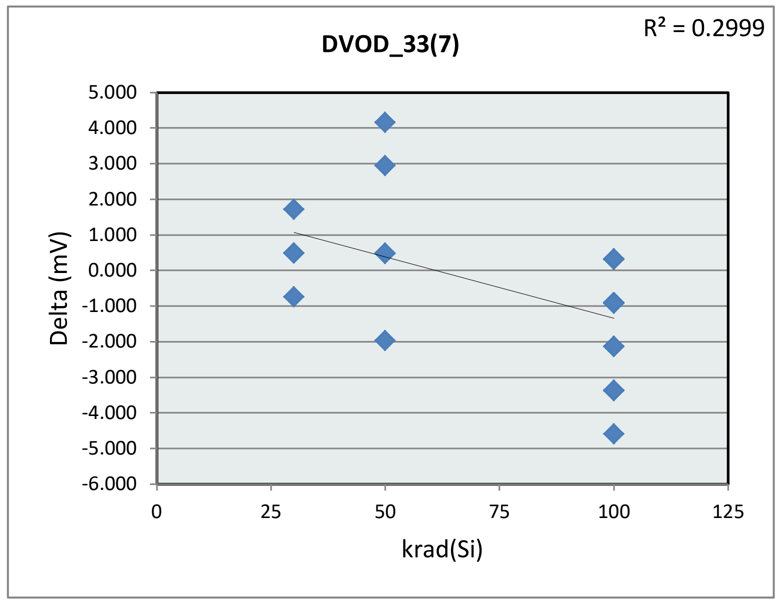


	VODL_33(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-396.435	-397.663	-414.662
Average	-394.963	-393.489	-401.273
Max	-391.529	-390.296	-393.798
UL	-255.000	-255.000	-255.000

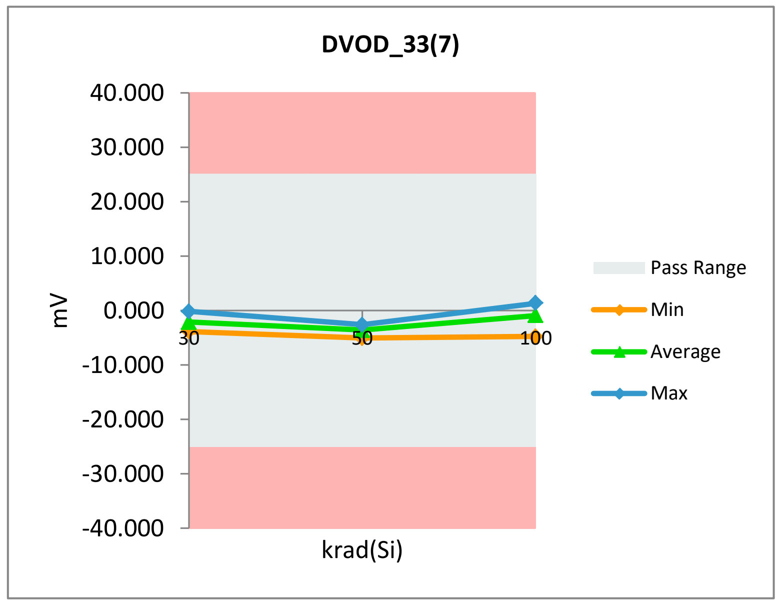


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.563	-0.145	1.708
30	2	-2.121	-2.602	0.481
30	3	-0.889	-1.369	0.480
30	4	-3.345	-2.598	-0.747
30	5	-3.350	-3.831	0.481
50	11	-5.800	-3.827	-1.973
50	12	-0.884	-3.826	2.942
50	13	-2.115	-2.590	0.475
50	14	-0.894	-5.054	4.160
50	15	-2.118	-2.595	0.477
100	22	-4.456	-1.083	-3.373
100	23	1.679	1.366	0.313
100	24	-0.777	0.131	-0.909
100	25	-4.456	-2.312	-2.144
100	26	-2.002	-1.086	-0.916
100	27	-5.682	-4.762	-0.920
100	28	-4.459	-3.551	-0.908
100	29	-0.772	-1.075	0.303
100	30	-2.004	0.132	-2.136
100	31	-0.776	-1.090	0.314
100	32	-0.776	-1.091	0.315
100	33	-2.003	-1.091	-0.912
100	34	-6.911	-2.310	-4.601
100	35	-0.773	0.149	-0.922
100	36	-2.003	-1.087	-0.916
100	37	-3.231	-2.319	-0.912
100	38	0.449	0.126	0.322
100	39	-2.004	0.136	-2.140
100	40	-5.682	-2.307	-3.375
100	41	-1.999	1.380	-3.379
100	42	-2.000	-1.080	-0.920
100	43	-0.775	1.366	-2.141
100	44	-0.775	1.366	-2.141
	Max	1.679	1.380	4.160
	Average	-2.186	-1.471	-0.716
	Min	-6.911	-5.054	-4.601
	Std Dev	2.048	1.774	1.802

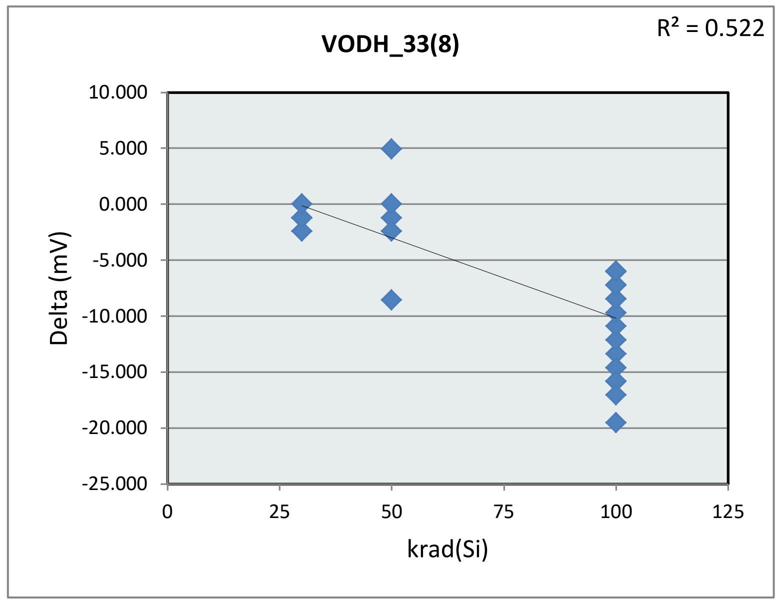


	DVOD_33(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-3.831	-5.054	-4.762
Average	-2.109	-3.578	-0.874
Max	-0.145	-2.590	1.380
UL	25.000	25.000	25.000

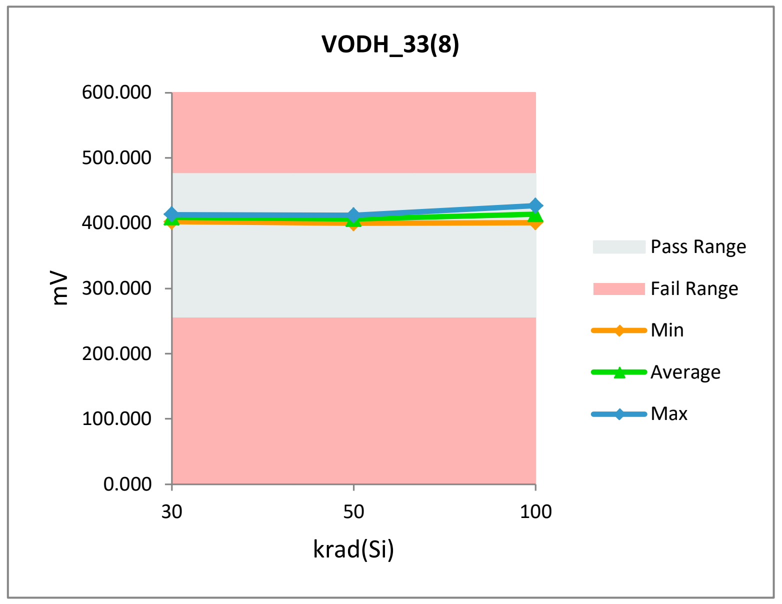


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	408.280	409.494	-1.214
30	2	399.691	402.130	-2.439
30	3	411.964	413.176	-1.212
30	4	407.055	408.267	-1.212
30	5	409.507	409.494	0.013
50	11	403.373	411.949	-8.576
50	12	408.282	403.358	4.924
50	13	407.058	408.267	-1.209
50	14	399.694	399.676	0.018
50	15	404.608	407.040	-2.432
100	22	400.856	415.460	-14.604
100	23	399.629	413.006	-13.377
100	24	402.083	414.232	-12.149
100	25	405.762	416.686	-10.924
100	26	404.538	411.778	-7.240
100	27	404.536	411.777	-7.241
100	28	405.764	413.005	-7.241
100	29	404.536	411.778	-7.242
100	30	403.314	410.552	-7.238
100	31	404.534	411.777	-7.243
100	32	403.309	410.550	-7.241
100	33	392.266	400.734	-8.468
100	34	406.995	426.505	-19.510
100	35	408.210	424.047	-15.837
100	36	404.542	419.143	-14.601
100	37	400.859	416.688	-15.829
100	38	395.948	413.006	-17.058
100	39	404.530	414.231	-9.701
100	40	402.078	408.095	-6.017
100	41	402.082	410.550	-8.468
100	42	403.312	410.551	-7.239
100	43	405.766	411.778	-6.012
100	44	405.766	411.778	-6.012
	Max	411.964	426.505	4.924
	Average	403.961	411.532	-7.571
	Min	392.266	399.676	-19.510
	Std Dev	3.880	5.617	5.687

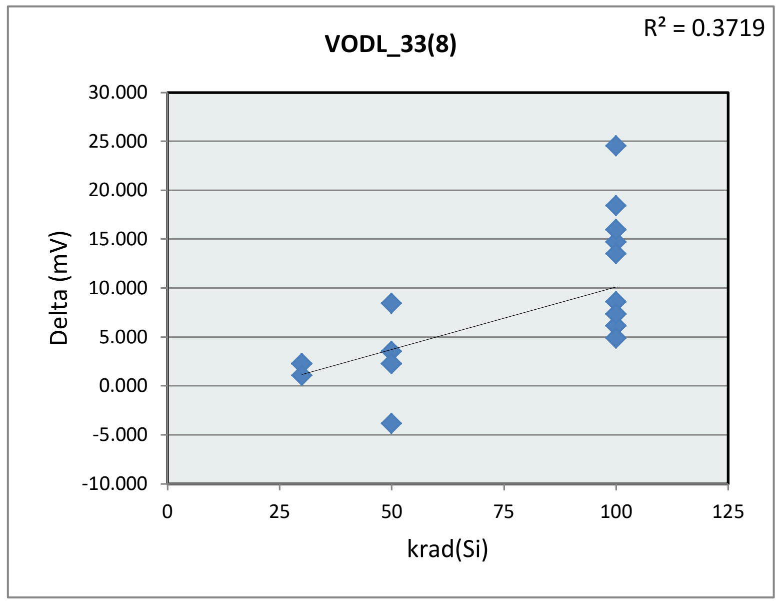


	VODH_33(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	402.130	399.676	400.734
Average	408.512	406.058	413.379
Max	413.176	411.949	426.505
UL	475.000	475.000	475.000

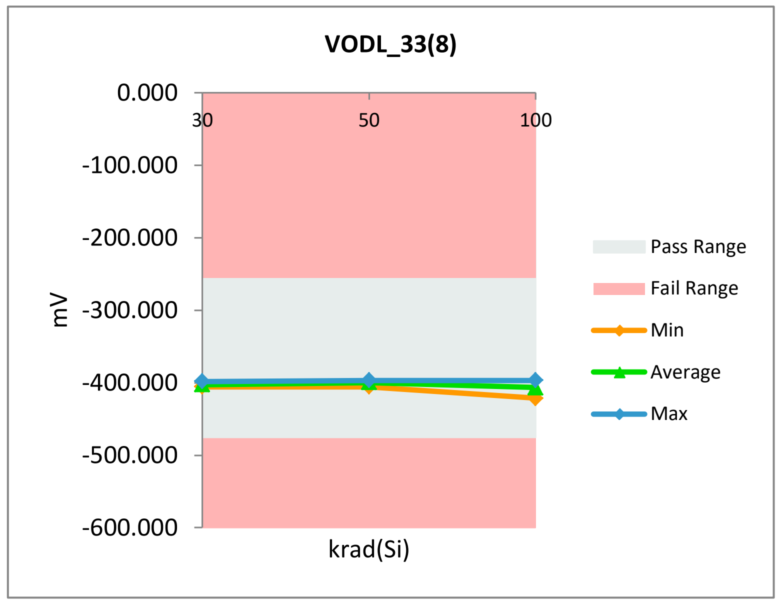


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-400.739	-403.014	2.275
30	2	-395.823	-398.104	2.281
30	3	-403.193	-405.469	2.276
30	4	-400.735	-403.014	2.279
30	5	-401.967	-403.014	1.047
50	11	-397.052	-405.469	8.417
50	12	-400.737	-396.877	-3.860
50	13	-398.277	-400.559	2.282
50	14	-394.593	-398.104	3.511
50	15	-394.589	-396.877	2.288
100	22	-393.246	-407.959	14.713
100	23	-392.018	-406.732	14.714
100	24	-396.928	-410.414	13.486
100	25	-399.386	-407.960	8.574
100	26	-398.155	-404.278	6.123
100	27	-399.385	-406.733	7.348
100	28	-400.612	-406.733	6.121
100	29	-395.703	-403.051	7.348
100	30	-394.471	-401.823	7.352
100	31	-398.160	-403.052	4.892
100	32	-398.157	-405.506	7.349
100	33	-390.791	-396.915	6.124
100	34	-396.926	-421.457	24.531
100	35	-403.075	-419.006	15.931
100	36	-398.151	-414.094	15.943
100	37	-394.471	-412.867	18.396
100	38	-390.790	-406.731	15.941
100	39	-399.390	-406.734	7.344
100	40	-396.934	-403.053	6.119
100	41	-395.702	-404.279	8.577
100	42	-395.700	-403.051	7.351
100	43	-396.928	-401.824	4.896
100	44	-396.928	-401.824	4.896
	Max	-390.790	-396.877	24.531
	Average	-397.264	-405.048	7.784
	Min	-403.193	-421.457	-3.860
	Std Dev	3.180	5.713	5.971



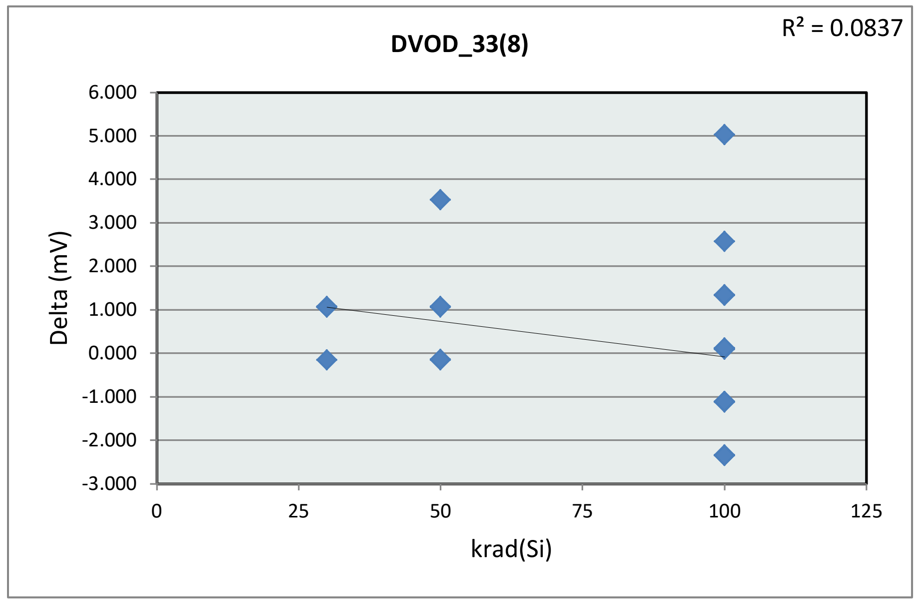
	VODL_33(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-405.469	-405.469	-421.457
Average	-402.523	-399.577	-406.786
Max	-398.104	-396.877	-396.915
UL	-255.000	-255.000	-255.000



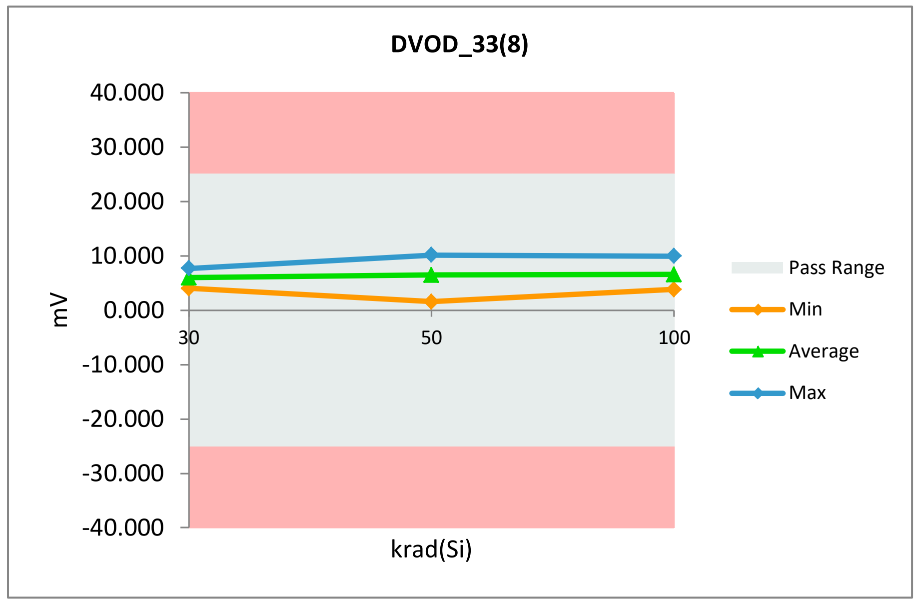
HDR TID Report T0 data
SN55LVCP22A-SP

	DVOD_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	7.541	6.480	1.061
30	2	3.868	4.026	-0.158
30	3	8.771	7.708	1.063
30	4	6.320	5.253	1.067
30	5	7.540	6.480	1.060
50	11	6.322	6.480	-0.158
50	12	7.546	6.481	1.065
50	13	8.781	7.708	1.073
50	14	5.101	1.572	3.529
50	15	10.019	10.163	-0.144
100	22	7.610	7.501	0.109
100	23	7.610	6.274	1.336
100	24	5.155	3.819	1.336
100	25	6.376	8.726	-2.350
100	26	6.383	7.500	-1.117
100	27	5.150	5.044	0.106
100	28	5.152	6.272	-1.120
100	29	8.833	8.727	0.106
100	30	8.843	8.729	0.114
100	31	6.374	8.725	-2.351
100	32	5.152	5.044	0.108
100	33	1.475	3.819	-2.344
100	34	10.069	5.048	5.021
100	35	5.135	5.041	0.094
100	36	6.391	5.049	1.342
100	37	6.388	3.821	2.567
100	38	5.158	6.275	-1.117
100	39	5.140	7.497	-2.357
100	40	5.143	5.042	0.101
100	41	6.380	6.272	0.108
100	42	7.612	7.500	0.112
100	43	8.839	9.954	-1.115
100	44	8.839	9.954	-1.115
	Max	10.069	10.163	5.021
	Average	6.697	6.484	0.213
	Min	1.475	1.572	-2.357
	Std Dev	1.870	2.019	1.615

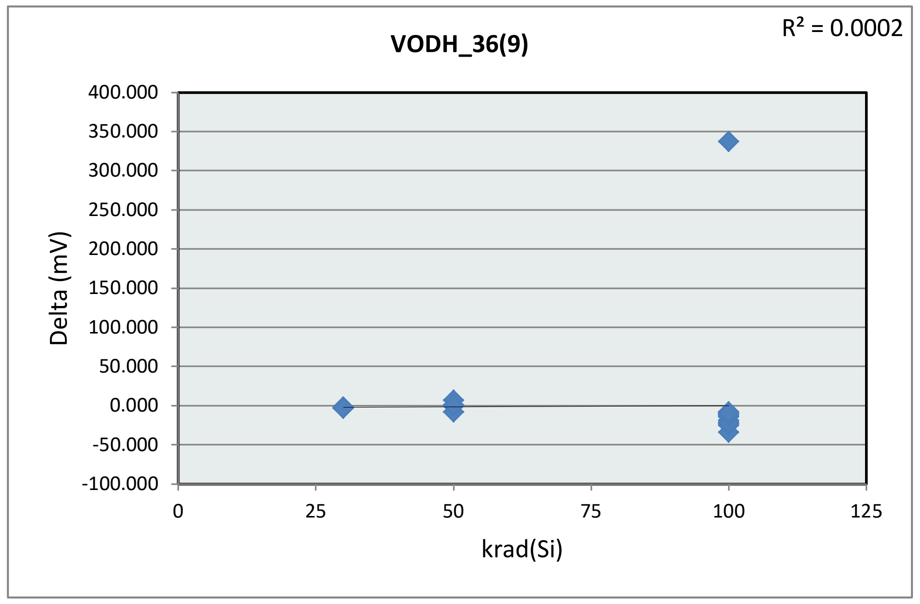


	DVOD_33(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	4.026	1.572	3.819
Average	5.989	6.481	6.593
Max	7.708	10.163	9.954
UL	25.000	25.000	25.000

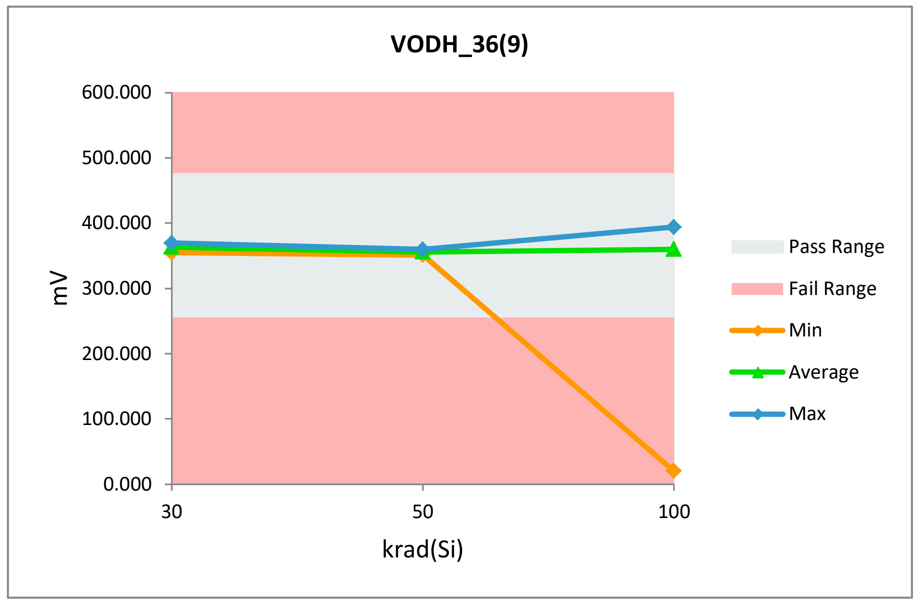


HDR TID Report T0 data
SN55LVCP22A-SP

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
		VODH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
30	1	363.451	366.835	-3.384
30	2	352.404	354.562	-2.158
30	3	357.316	359.473	-2.157
30	4	367.134	369.290	-2.156
30	5	363.449	366.833	-3.384
50	11	351.178	359.471	-8.293
50	12	357.318	350.883	6.435
50	13	357.316	358.250	-0.934
50	14	353.632	354.563	-0.931
50	15	357.315	357.020	0.295
100	22	357.347	380.443	-23.096
100	23	357.346	380.439	-23.093
100	24	363.482	382.890	-19.408
100	25	357.347	20.124	337.223
100	26	359.801	369.398	-9.597
100	27	354.893	366.945	-12.052
100	28	359.800	369.392	-9.592
100	29	358.576	368.177	-9.601
100	30	367.163	376.756	-9.593
100	31	363.483	374.304	-10.821
100	32	361.028	369.395	-8.367
100	33	351.210	359.579	-8.369
100	34	359.801	393.940	-34.139
100	35	365.938	391.488	-25.550
100	36	357.346	379.212	-21.866
100	37	362.255	385.346	-23.091
100	38	361.027	382.888	-21.861
100	39	365.937	380.439	-14.502
100	40	354.893	366.947	-12.054
100	41	353.666	366.950	-13.284
100	42	359.802	370.629	-10.827
100	43	363.483	373.078	-9.595
100	44	363.483	373.078	-9.595
	Max	367.163	393.940	337.223
	Average	359.382	359.970	-0.588
	Min	351.178	20.124	-34.139
	Std Dev	4.488	61.928	61.291

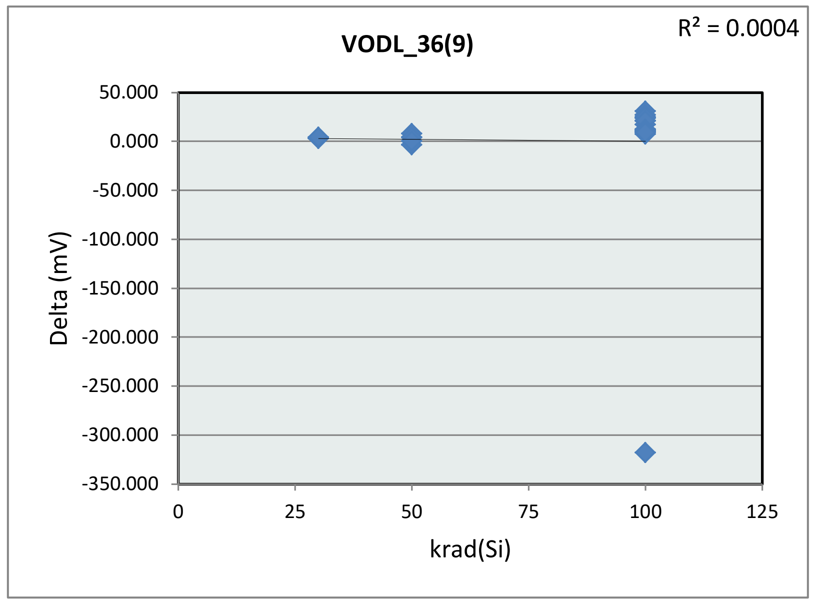


	VODH_36(9)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	354.562	350.883	20.124
Average	363.399	356.037	360.080
Max	369.290	359.471	393.940
UL	475.000	475.000	475.000

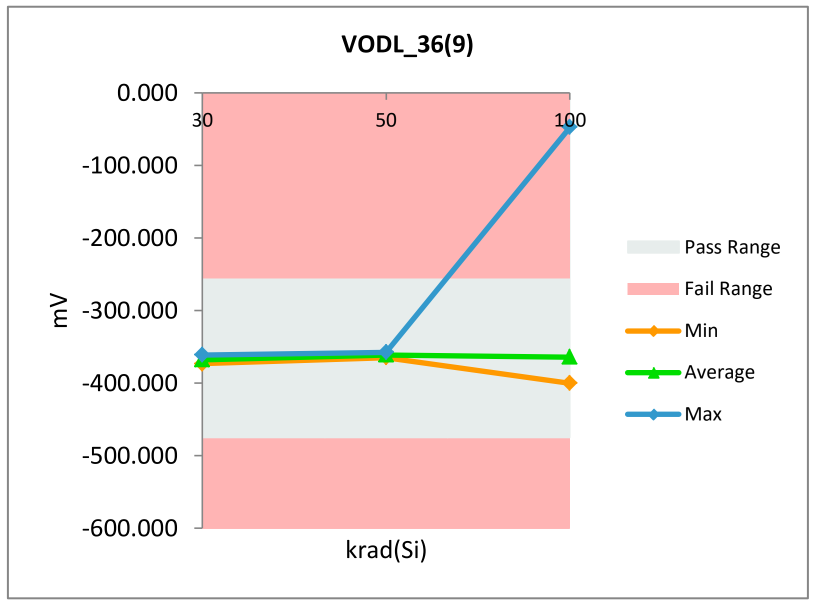


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-365.577	-368.216	2.639
30	2	-356.987	-360.855	3.868
30	3	-361.894	-364.533	2.639
30	4	-370.486	-373.124	2.638
30	5	-368.034	-371.900	3.866
50	11	-356.986	-364.536	7.550
50	12	-360.664	-357.172	-3.492
50	13	-358.212	-362.076	3.864
50	14	-356.987	-360.854	3.867
50	15	-360.668	-360.852	0.184
100	22	-363.033	-383.992	20.959
100	23	-355.670	-379.088	23.418
100	24	-365.489	-382.772	17.283
100	25	-365.488	-47.365	-318.123
100	26	-360.579	-370.497	9.918
100	27	-363.033	-374.176	11.143
100	28	-365.489	-375.410	9.921
100	29	-361.805	-372.945	11.140
100	30	-370.398	-380.317	9.919
100	31	-366.715	-376.633	9.918
100	32	-363.034	-371.727	8.693
100	33	-355.670	-363.137	7.467
100	34	-369.170	-399.944	30.774
100	35	-365.487	-392.579	27.092
100	36	-360.579	-381.542	20.963
100	37	-364.262	-388.905	24.643
100	38	-363.035	-384.001	20.966
100	39	-370.397	-382.769	12.372
100	40	-363.032	-372.947	9.915
100	41	-356.896	-369.263	12.367
100	42	-361.805	-371.720	9.915
100	43	-365.488	-374.179	8.691
100	44	-365.488	-374.179	8.691
	Max	-355.670	-47.365	30.774
	Average	-362.986	-364.067	1.081
	Min	-370.486	-399.944	-318.123
	Std Dev	4.297	57.686	57.878

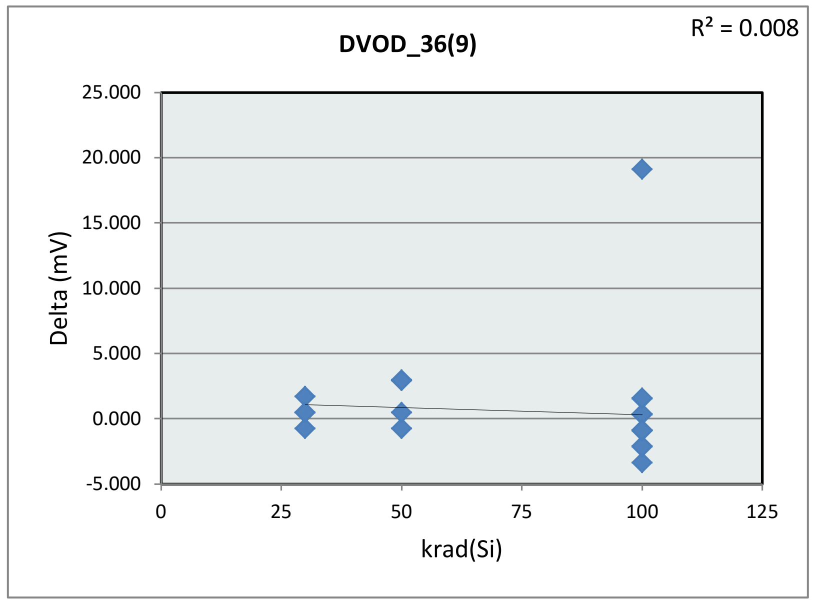


	VODL_36(9)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-373.124	-364.536	-399.944
Average	-367.726	-361.098	-363.917
Max	-360.855	-357.172	-47.365
UL	-255.000	-255.000	-255.000

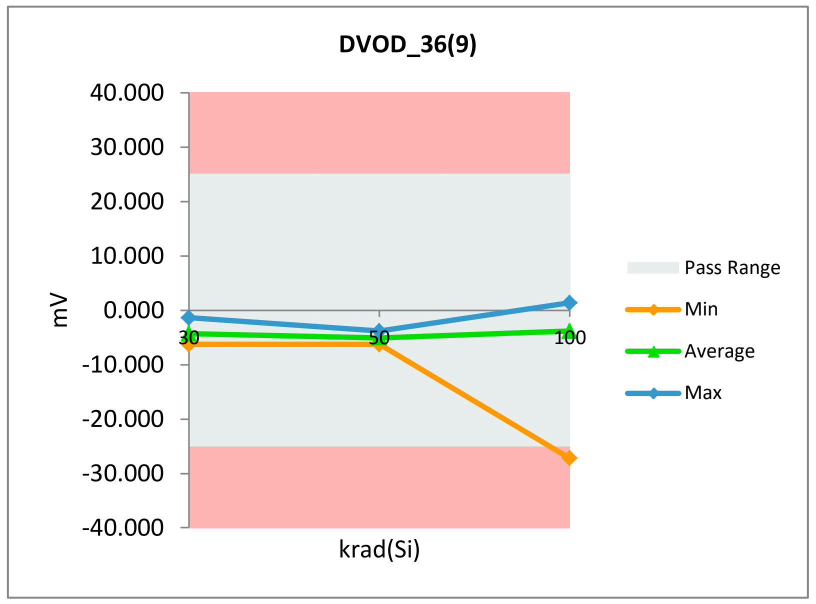


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-2.126	-1.381	-0.745
30	2	-4.583	-6.293	1.710
30	3	-4.578	-5.060	0.482
30	4	-3.352	-3.834	0.482
30	5	-4.584	-5.067	0.483
50	11	-5.807	-5.065	-0.742
50	12	-3.346	-6.289	2.943
50	13	-0.896	-3.826	2.930
50	14	-3.355	-6.291	2.936
50	15	-3.353	-3.832	0.479
100	22	-5.686	-3.549	-2.137
100	23	1.676	1.352	0.324
100	24	-2.007	0.118	-2.125
100	25	-8.141	-27.242	19.101
100	26	-0.777	-1.099	0.322
100	27	-8.140	-7.231	-0.909
100	28	-5.689	-6.019	0.330
100	29	-3.229	-4.768	1.539
100	30	-3.234	-3.562	0.328
100	31	-3.233	-2.329	-0.904
100	32	-2.006	-2.331	0.325
100	33	-4.460	-3.558	-0.902
100	34	-9.369	-6.004	-3.365
100	35	0.451	-1.091	1.542
100	36	-3.233	-2.329	-0.904
100	37	-2.007	-3.559	1.552
100	38	-2.009	-1.113	-0.896
100	39	-4.461	-2.330	-2.131
100	40	-8.139	-6.000	-2.139
100	41	-3.229	-2.313	-0.916
100	42	-2.003	-1.091	-0.912
100	43	-2.005	-1.100	-0.905
100	44	-2.005	-1.100	-0.905
	Max	1.676	1.352	19.101
	Average	-3.604	-4.097	0.493
	Min	-9.369	-27.242	-3.365
	Std Dev	2.459	4.677	3.675

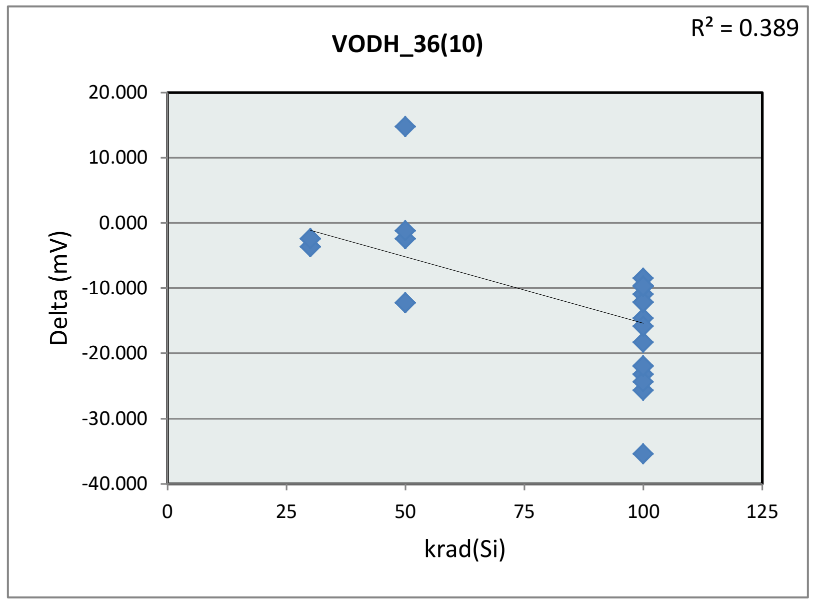


	DVOD_36(9)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-6.293	-6.291	-27.242
Average	-4.327	-5.061	-3.837
Max	-1.381	-3.826	1.352
UL	25.000	25.000	25.000

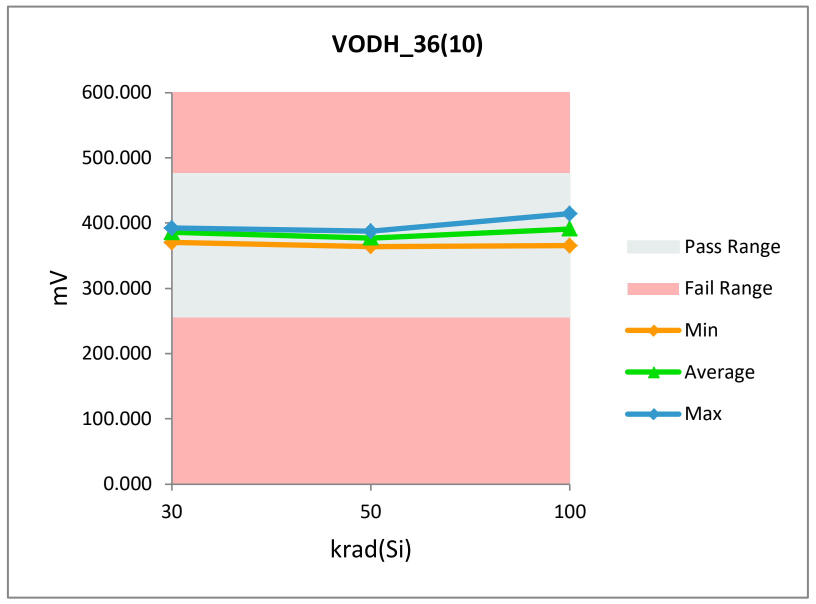


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	384.950	387.402	-2.452
30	2	366.539	370.219	-3.680
30	3	386.177	388.629	-2.452
30	4	386.180	389.856	-3.676
30	5	389.859	392.311	-2.452
50	11	371.449	383.720	-12.271
50	12	387.407	372.674	14.733
50	13	375.134	387.402	-12.268
50	14	361.631	364.082	-2.451
50	15	376.367	377.583	-1.216
100	22	375.074	398.278	-23.204
100	23	362.799	386.006	-23.207
100	24	373.846	392.142	-18.296
100	25	379.980	394.595	-14.615
100	26	373.846	383.551	-9.705
100	27	377.525	388.459	-10.934
100	28	375.072	384.778	-9.706
100	29	377.527	387.233	-9.706
100	30	381.214	390.915	-9.701
100	31	378.752	387.232	-8.480
100	32	373.844	383.551	-9.707
100	33	355.437	365.144	-9.707
100	34	378.759	414.232	-35.473
100	35	386.110	411.774	-25.664
100	36	373.850	395.824	-21.974
100	37	372.622	397.051	-24.429
100	38	360.347	382.325	-21.978
100	39	383.658	399.503	-15.845
100	40	378.750	390.913	-12.163
100	41	373.845	386.005	-12.160
100	42	378.757	390.915	-12.158
100	43	379.984	389.687	-9.703
100	44	379.984	389.687	-9.703
	Max	389.859	414.232	14.733
	Average	376.281	387.990	-11.709
	Min	355.437	364.082	-35.473
	Std Dev	8.050	10.626	9.339

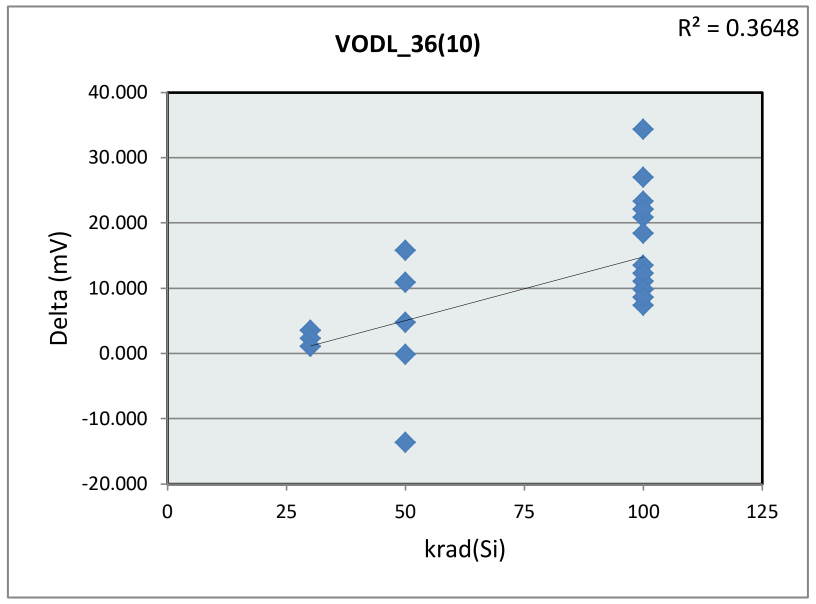


	VODH_36(10)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	370.219	364.082	365.144
Average	385.683	377.092	390.861
Max	392.311	387.402	414.232
UL	475.000	475.000	475.000

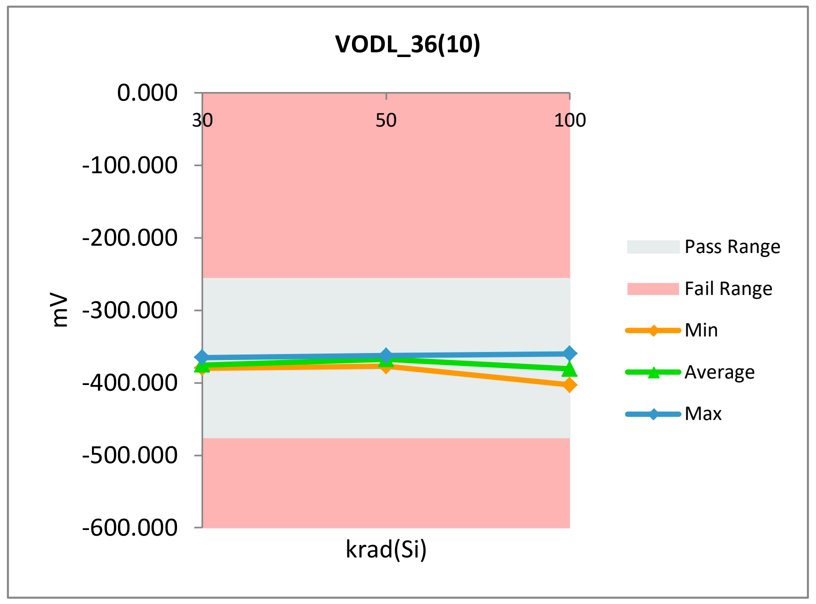


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-374.963	-378.467	3.504
30	2	-361.455	-364.966	3.511
30	3	-373.736	-376.012	2.276
30	4	-378.643	-379.694	1.051
30	5	-377.419	-378.467	1.048
50	11	-362.683	-373.558	10.875
50	12	-376.189	-362.511	-13.678
50	13	-361.453	-377.240	15.787
50	14	-357.769	-362.511	4.742
50	15	-362.676	-362.511	-0.165
100	22	-363.796	-385.872	22.076
100	23	-353.979	-374.829	20.850
100	24	-365.025	-383.419	18.394
100	25	-369.937	-383.419	13.482
100	26	-363.797	-373.601	9.804
100	27	-368.710	-379.738	11.028
100	28	-366.253	-377.283	11.030
100	29	-366.253	-376.056	9.803
100	30	-367.476	-377.282	9.806
100	31	-368.711	-377.284	8.573
100	32	-365.026	-374.829	9.803
100	33	-352.751	-360.103	7.352
100	34	-366.249	-400.597	34.348
100	35	-376.081	-403.055	26.974
100	36	-365.020	-387.099	22.079
100	37	-363.794	-387.099	23.305
100	38	-353.977	-376.055	22.078
100	39	-374.850	-387.102	12.252
100	40	-372.394	-382.193	9.799
100	41	-366.253	-378.510	12.257
100	42	-369.932	-379.737	9.805
100	43	-367.478	-376.056	8.578
100	44	-367.478	-376.056	8.578
	Max	-352.751	-360.103	34.348
	Average	-366.734	-377.976	11.243
	Min	-378.643	-403.055	-13.678
	Std Dev	6.621	9.396	9.187

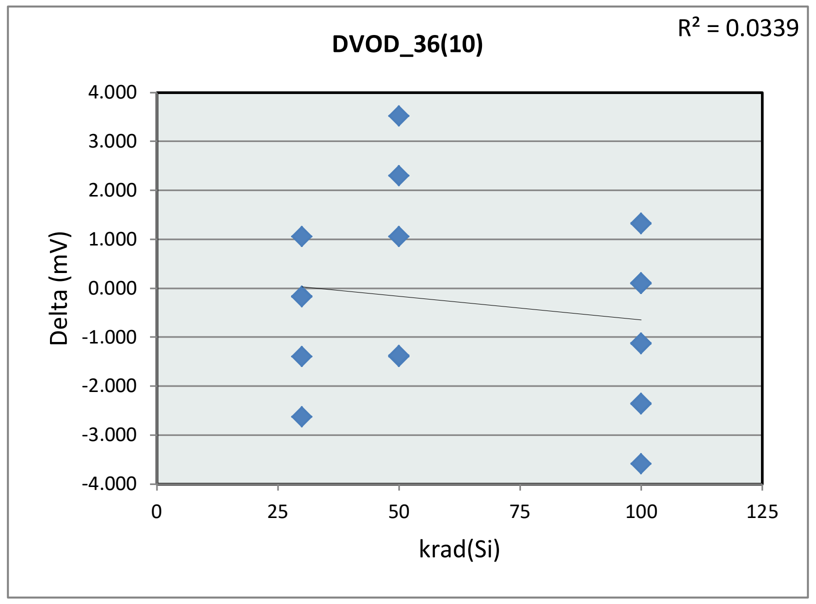


	VODL_36(10)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-379.694	-377.240	-403.055
Average	-375.521	-367.666	-380.751
Max	-364.966	-362.511	-360.103
UL	-255.000	-255.000	-255.000

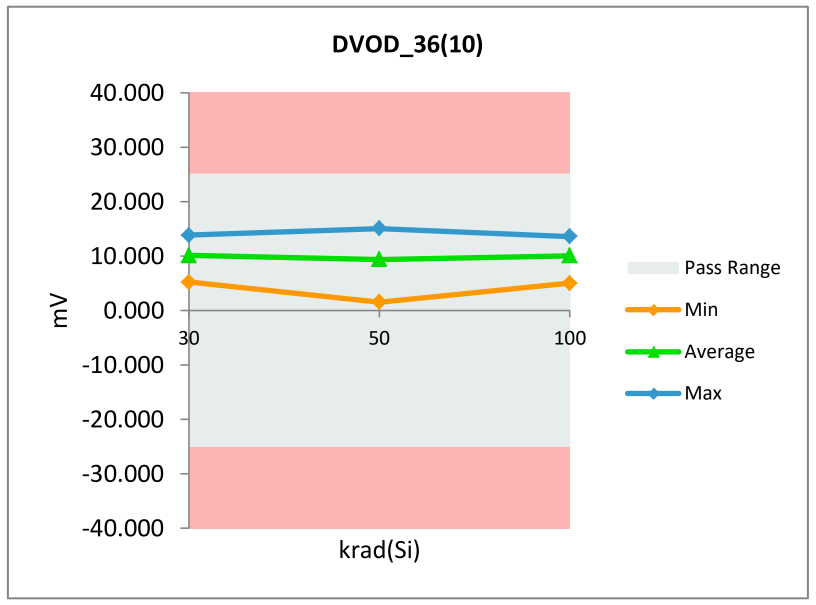


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	9.987	8.935	1.052
30	2	5.085	5.253	-0.168
30	3	12.441	12.617	-0.176
30	4	7.537	10.162	-2.625
30	5	12.440	13.844	-1.404
50	11	8.765	10.162	-1.397
50	12	11.218	10.162	1.056
50	13	13.681	10.162	3.519
50	14	3.862	1.571	2.291
50	15	13.691	15.072	-1.381
100	22	11.278	12.405	-1.127
100	23	8.820	11.177	-2.357
100	24	8.821	8.723	0.098
100	25	10.043	11.176	-1.133
100	26	10.049	9.950	0.099
100	27	8.816	8.722	0.094
100	28	8.818	7.495	1.323
100	29	11.274	11.177	0.097
100	30	13.738	13.633	0.105
100	31	10.041	9.948	0.093
100	32	8.818	8.721	0.097
100	33	2.686	5.041	-2.355
100	34	12.509	13.634	-1.125
100	35	10.029	8.719	1.310
100	36	8.830	8.726	0.104
100	37	8.828	9.952	-1.124
100	38	6.370	6.270	0.100
100	39	8.808	12.401	-3.593
100	40	6.356	8.720	-2.364
100	41	7.592	7.495	0.097
100	42	8.825	11.178	-2.353
100	43	12.506	13.632	-1.126
100	44	12.506	13.632	-1.126
	Max	13.738	15.072	3.519
	Average	9.547	10.014	-0.467
	Min	2.686	1.571	-3.593
	Std Dev	2.725	2.920	1.497

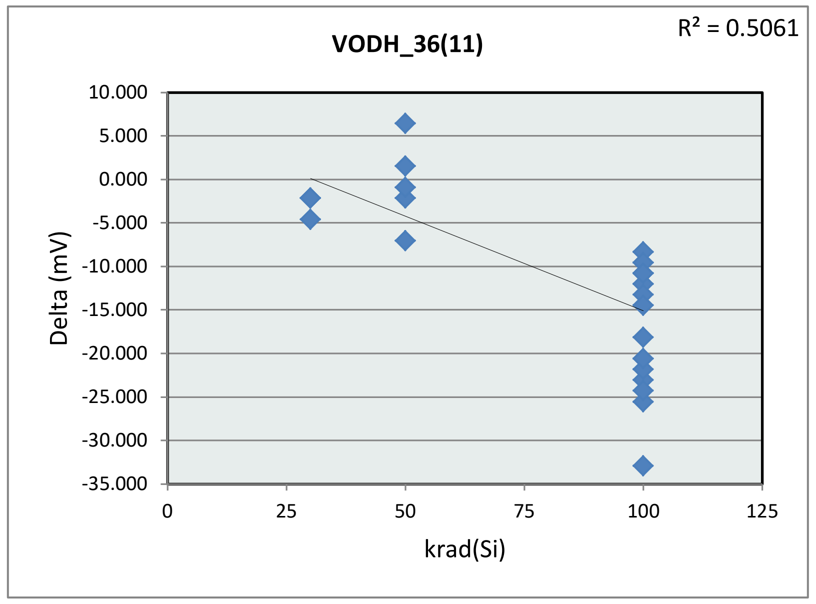


	DVOD_36(10)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	5.253	1.571	5.041
Average	10.162	9.426	10.110
Max	13.844	15.072	13.634
UL	25.000	25.000	25.000

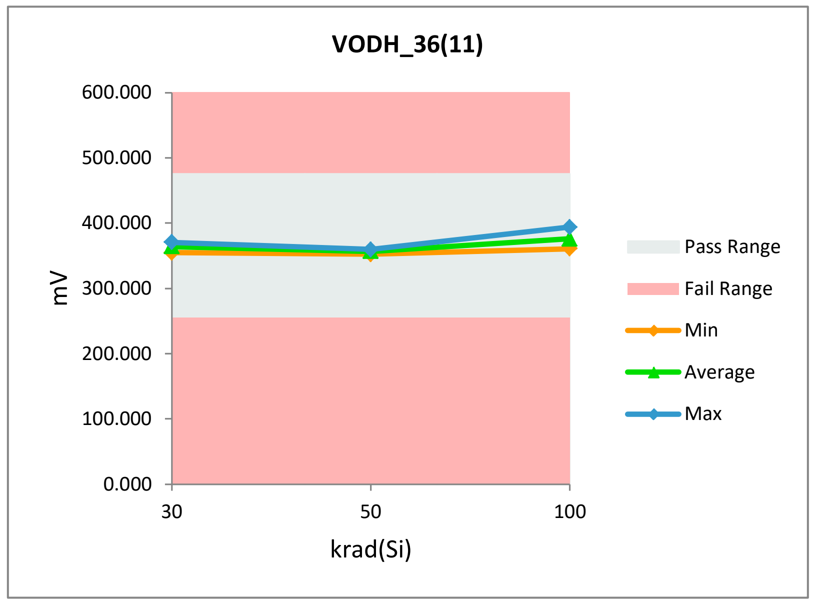


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	364.677	366.834	-2.157
30	2	352.403	354.561	-2.158
30	3	358.541	360.699	-2.158
30	4	365.905	370.516	-4.611
30	5	364.675	366.831	-2.156
50	11	352.404	359.469	-7.065
50	12	358.544	352.108	6.436
50	13	356.087	358.248	-2.161
50	14	354.857	355.789	-0.932
50	15	358.541	357.018	1.523
100	22	358.574	379.214	-20.640
100	23	357.346	380.438	-23.092
100	24	363.481	381.661	-18.180
100	25	358.573	373.078	-14.505
100	26	359.801	369.396	-9.595
100	27	356.120	368.170	-12.050
100	28	358.572	370.616	-12.044
100	29	358.575	369.402	-10.827
100	30	367.163	376.754	-9.591
100	31	365.937	374.302	-8.365
100	32	362.255	370.620	-8.365
100	33	351.210	360.804	-9.594
100	34	361.028	393.938	-32.910
100	35	365.938	391.486	-25.548
100	36	357.345	379.210	-21.865
100	37	361.027	385.344	-24.317
100	38	362.253	382.886	-20.633
100	39	365.936	379.210	-13.274
100	40	356.120	366.945	-10.825
100	41	353.666	368.175	-14.509
100	42	361.029	371.854	-10.825
100	43	363.482	374.303	-10.821
100	44	363.482	374.303	-10.821
	Max	367.163	393.938	6.436
	Average	359.865	371.036	-11.171
	Min	351.210	352.108	-32.910
	Std Dev	4.395	10.310	8.716



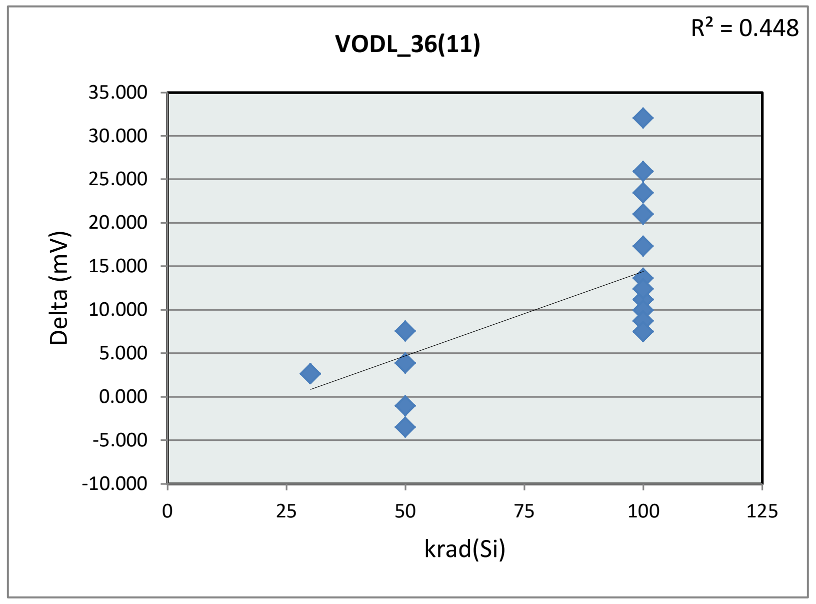
	VODH_36(11)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	354.561	352.108	360.804
Average	363.888	356.526	375.744
Max	370.516	359.469	393.938
UL	475.000	475.000	475.000



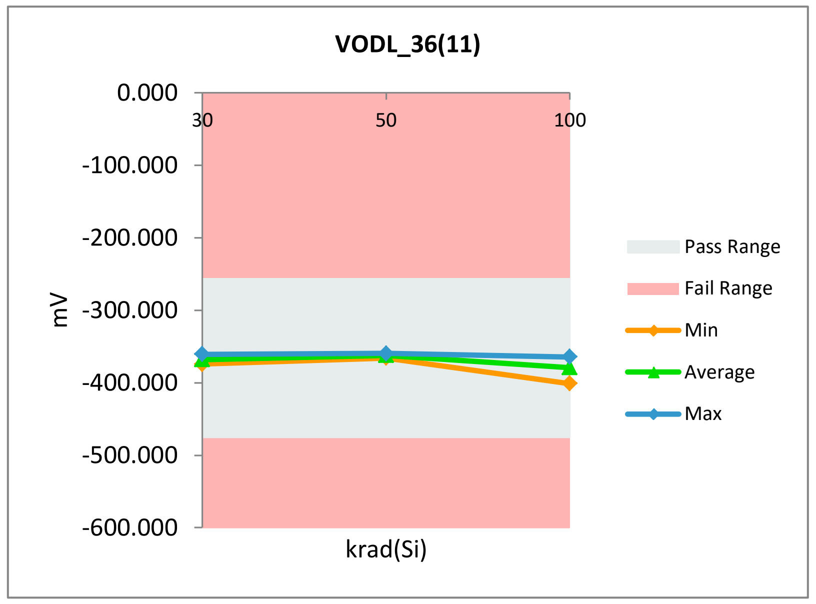
HDR TID Report T0 data
SN55LVCP22A-SP

	VODL_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-255	-255
Min Limit	-475	-475

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-366.806	-369.444	2.638
30	2	-358.215	-360.857	2.642
30	3	-361.895	-364.535	2.640
30	4	-371.714	-374.353	2.639
30	5	-369.262	-371.901	2.639
50	11	-358.214	-365.765	7.551
50	12	-363.120	-359.627	-3.493
50	13	-359.440	-363.304	3.864
50	14	-358.216	-362.082	3.866
50	15	-361.896	-360.853	-1.043
100	22	-363.034	-383.994	20.960
100	23	-356.898	-380.316	23.418
100	24	-366.717	-384.001	17.284
100	25	-366.716	-380.314	13.598
100	26	-361.807	-371.726	9.919
100	27	-363.033	-374.178	11.145
100	28	-365.490	-376.640	11.150
100	29	-361.805	-372.947	11.142
100	30	-371.625	-380.319	8.694
100	31	-367.943	-377.862	9.919
100	32	-363.034	-372.956	9.922
100	33	-356.898	-364.366	7.468
100	34	-369.170	-401.173	32.003
100	35	-366.715	-392.581	25.866
100	36	-361.807	-382.771	20.964
100	37	-365.489	-388.908	23.419
100	38	-364.263	-385.231	20.968
100	39	-370.398	-382.771	12.373
100	40	-364.260	-372.949	8.689
100	41	-358.124	-370.493	12.369
100	42	-363.033	-371.722	8.689
100	43	-366.716	-374.181	7.465
100	44	-366.716	-374.181	7.465
	Max	-356.898	-359.627	32.003
	Average	-363.954	-374.827	10.874
	Min	-371.714	-401.173	-3.493
	Std Dev	4.192	9.707	8.279

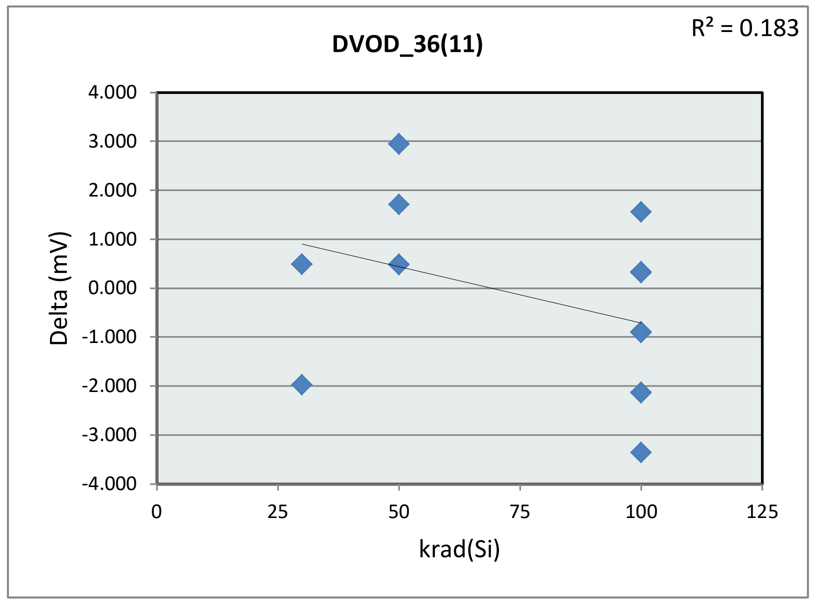


	VODL_36(11)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-374.353	-365.765	-401.173
Average	-368.218	-362.326	-378.982
Max	-360.857	-359.627	-364.366
UL	-255.000	-255.000	-255.000

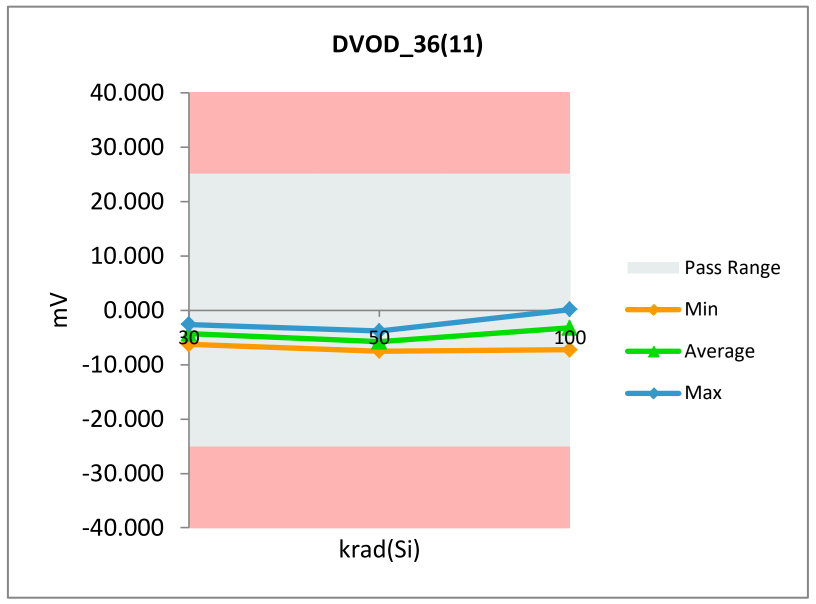


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-2.128	-2.611	0.483
30	2	-5.812	-6.296	0.484
30	3	-3.354	-3.836	0.482
30	4	-5.809	-3.837	-1.972
30	5	-4.587	-5.070	0.483
50	11	-5.810	-6.295	0.485
50	12	-4.575	-7.519	2.944
50	13	-3.353	-5.056	1.703
50	14	-3.358	-6.293	2.935
50	15	-3.355	-3.835	0.480
100	22	-4.460	-4.780	0.320
100	23	0.447	0.121	0.326
100	24	-3.236	-2.341	-0.895
100	25	-8.142	-7.237	-0.905
100	26	-2.006	-2.330	0.324
100	27	-6.914	-6.008	-0.906
100	28	-6.918	-6.023	-0.895
100	29	-3.230	-3.545	0.315
100	30	-4.462	-3.565	-0.897
100	31	-2.006	-3.560	1.554
100	32	-0.780	-2.336	1.556
100	33	-5.689	-3.563	-2.126
100	34	-8.142	-7.235	-0.907
100	35	-0.777	-1.095	0.318
100	36	-4.462	-3.561	-0.901
100	37	-4.462	-3.563	-0.899
100	38	-2.010	-2.345	0.335
100	39	-4.462	-3.560	-0.902
100	40	-8.140	-6.004	-2.136
100	41	-4.458	-2.318	-2.140
100	42	-2.004	0.132	-2.136
100	43	-3.233	0.123	-3.356
100	44	-3.233	0.123	-3.356
	Max	0.447	0.132	2.944
	Average	-4.088	-3.791	-0.297
	Min	-8.142	-7.519	-3.356
	Std Dev	2.142	2.211	1.542

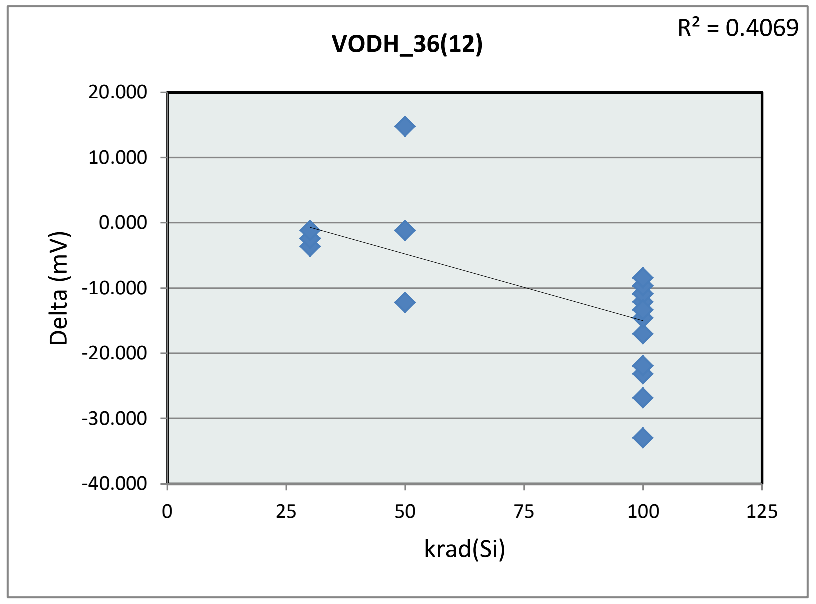


	DVOD_36(11)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-6.296	-7.519	-7.237
Average	-4.330	-5.800	-3.238
Max	-2.611	-3.835	0.132
UL	25.000	25.000	25.000

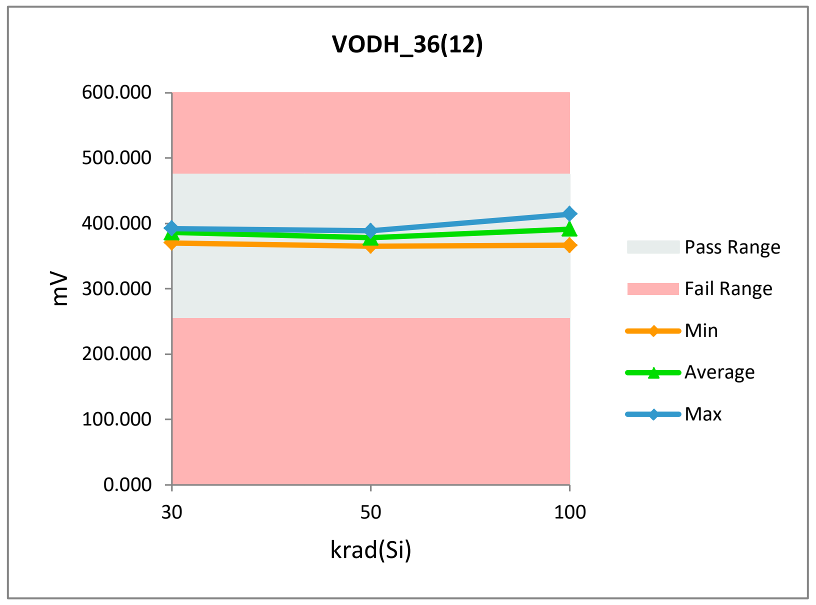


HDR TID Report T0 data
SN55LVCP22A-SP

		VODH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	475	475	
	Min Limit	255	255	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	384.948	387.402	-2.454
30	2	367.766	370.219	-2.453
30	3	386.176	389.856	-3.680
30	4	387.406	389.856	-2.450
30	5	391.086	392.311	-1.225
50	11	372.675	384.947	-12.272
50	12	387.405	372.674	14.731
50	13	376.361	388.629	-12.268
50	14	364.084	365.309	-1.225
50	15	376.365	377.583	-1.218
100	22	376.300	398.277	-21.977
100	23	364.024	386.005	-21.981
100	24	376.298	393.368	-17.070
100	25	381.205	394.595	-13.390
100	26	375.071	386.005	-10.934
100	27	377.524	389.686	-12.162
100	28	375.069	386.005	-10.936
100	29	377.525	388.460	-10.935
100	30	381.212	390.915	-9.703
100	31	378.750	388.459	-9.709
100	32	375.069	383.550	-8.481
100	33	356.662	366.371	-9.709
100	34	381.211	414.231	-33.020
100	35	384.881	411.773	-26.892
100	36	375.075	397.051	-21.976
100	37	373.847	397.051	-23.204
100	38	361.572	383.552	-21.980
100	39	384.884	399.502	-14.618
100	40	379.975	390.912	-10.937
100	41	372.616	386.005	-13.389
100	42	379.983	389.687	-9.704
100	43	381.210	389.687	-8.477
100	44	381.210	389.687	-8.477
	Max	391.086	414.231	14.731
	Average	377.135	388.473	-11.339
	Min	356.662	365.309	-33.020
	Std Dev	7.771	10.431	9.148

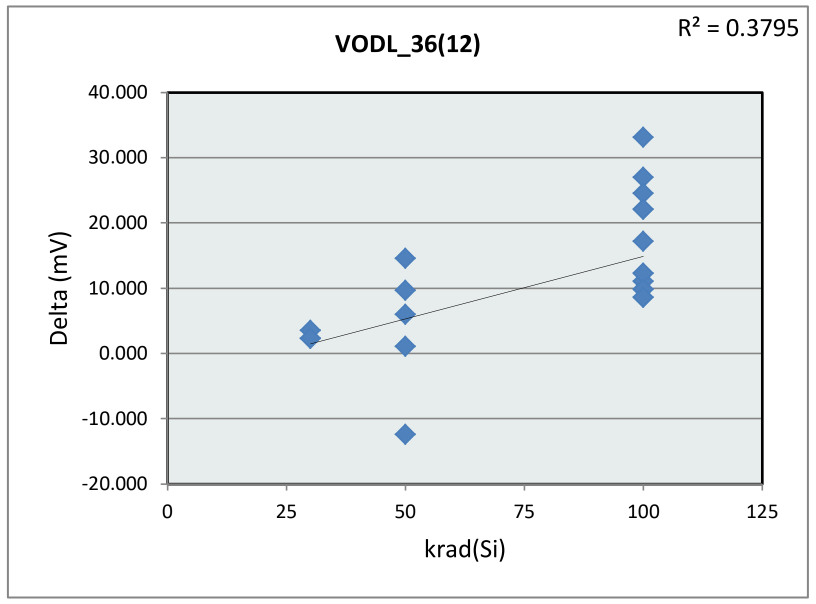


	VODH_36(12)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	475	mV	
Min Limit	255	mV	
krad(Si)	30	50	100
LL	255.000	255.000	255.000
Min	370.219	365.309	366.371
Average	385.929	377.828	391.341
Max	392.311	388.629	414.231
UL	475.000	475.000	475.000

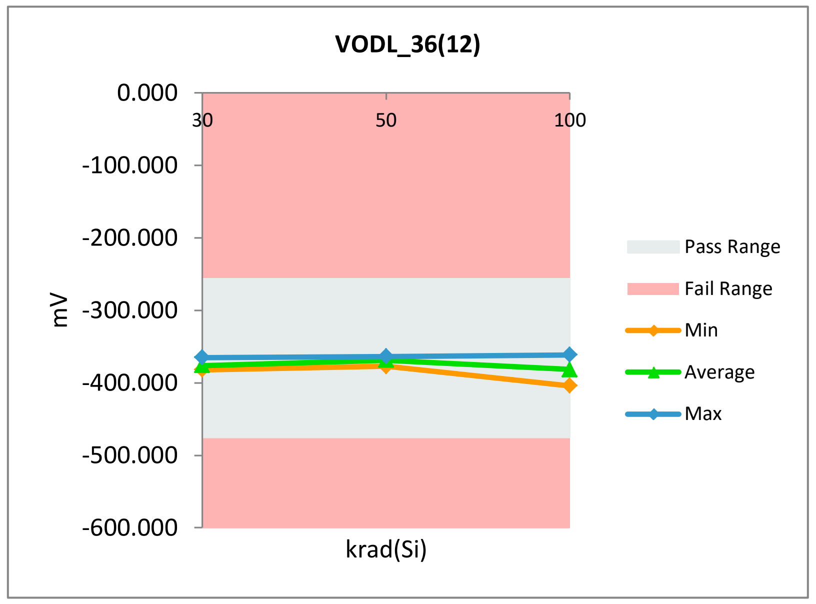


HDR TID Report T0 data
SN55LVCP22A-SP

		VODL_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-255	-255	
	Min Limit	-475	-475	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-376.192	-378.467	2.275
30	2	-362.684	-364.966	2.282
30	3	-373.737	-376.012	2.275
30	4	-378.645	-382.149	3.504
30	5	-377.421	-379.694	2.273
50	11	-365.140	-374.785	9.645
50	12	-376.190	-363.739	-12.451
50	13	-362.683	-377.240	14.557
50	14	-357.771	-363.739	5.968
50	15	-362.677	-363.739	1.062
100	22	-365.026	-387.100	22.074
100	23	-353.982	-376.056	22.074
100	24	-367.482	-384.646	17.164
100	25	-371.167	-383.420	12.253
100	26	-365.026	-374.829	9.803
100	27	-368.711	-380.965	12.254
100	28	-368.711	-378.511	9.800
100	29	-366.255	-377.284	11.029
100	30	-368.705	-378.509	9.804
100	31	-368.713	-378.511	9.798
100	32	-366.256	-374.830	8.574
100	33	-352.753	-361.331	8.578
100	34	-367.478	-400.598	33.120
100	35	-377.310	-404.283	26.973
100	36	-366.250	-388.326	22.076
100	37	-363.796	-388.327	24.531
100	38	-353.979	-376.056	22.077
100	39	-374.852	-387.102	12.250
100	40	-372.396	-383.421	11.025
100	41	-366.255	-378.511	12.256
100	42	-371.162	-380.965	9.803
100	43	-368.708	-377.283	8.575
100	44	-368.708	-377.283	8.575
	Max	-352.753	-361.331	33.120
	Average	-367.479	-378.869	11.390
	Min	-378.645	-404.283	-12.451
	Std Dev	6.632	9.353	8.904

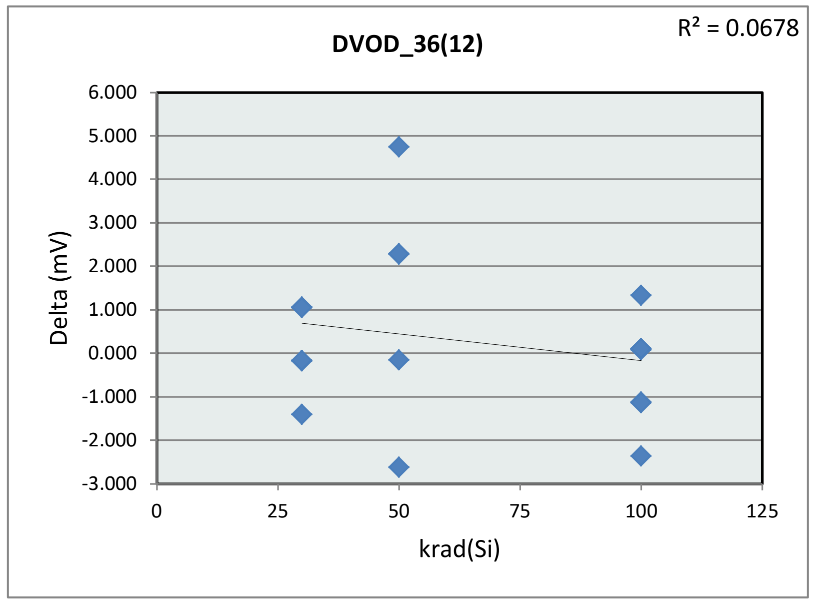


	VODL_36(12)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	-255	mV	
Min Limit	-475	mV	
krad(Si)	30	50	100
LL	-475.000	-475.000	-475.000
Min	-382.149	-377.240	-404.283
Average	-376.258	-368.648	-381.659
Max	-364.966	-363.739	-361.331
UL	-255.000	-255.000	-255.000

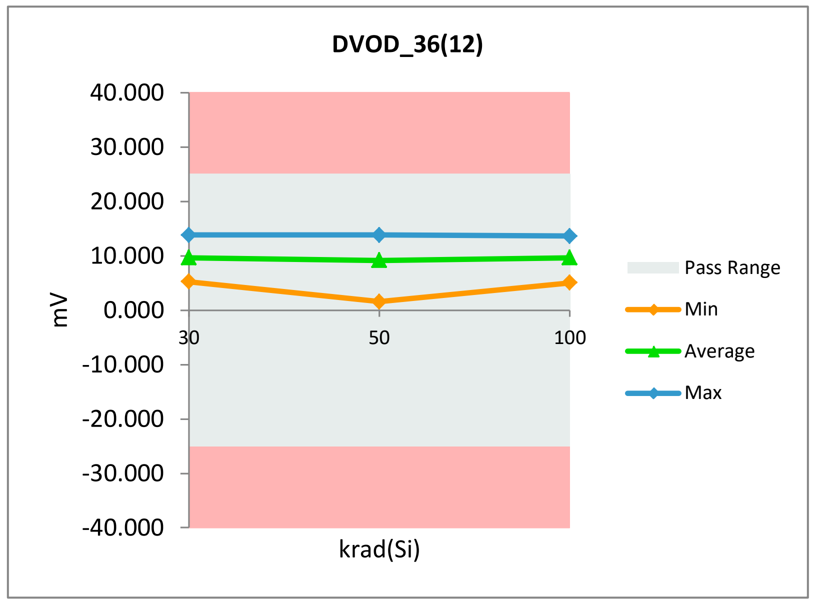


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOD_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	8.756	8.935	-0.179
30	2	5.082	5.253	-0.171
30	3	12.439	13.844	-1.405
30	4	8.762	7.707	1.055
30	5	13.665	12.617	1.048
50	11	7.535	10.162	-2.627
50	12	11.215	8.935	2.280
50	13	13.678	11.389	2.289
50	14	6.314	1.571	4.743
50	15	13.688	13.844	-0.156
100	22	11.274	11.177	0.097
100	23	10.042	9.949	0.093
100	24	8.816	8.722	0.094
100	25	10.039	11.175	-1.136
100	26	10.045	11.176	-1.131
100	27	8.812	8.720	0.092
100	28	6.359	7.493	-1.134
100	29	11.270	11.176	0.094
100	30	12.507	12.405	0.102
100	31	10.037	9.947	0.090
100	32	8.813	8.720	0.093
100	33	3.909	5.040	-1.131
100	34	13.733	13.633	0.100
100	35	7.570	7.490	0.080
100	36	8.826	8.725	0.101
100	37	10.051	8.724	1.327
100	38	7.592	7.496	0.096
100	39	10.032	12.400	-2.368
100	40	7.579	7.491	0.088
100	41	6.361	7.494	-1.133
100	42	8.821	8.723	0.098
100	43	12.502	12.404	0.098
100	44	12.502	12.404	0.098
	Max	13.733	13.844	4.743
	Average	9.655	9.604	0.051
	Min	3.909	1.571	-2.627
	Std Dev	2.593	2.750	1.346

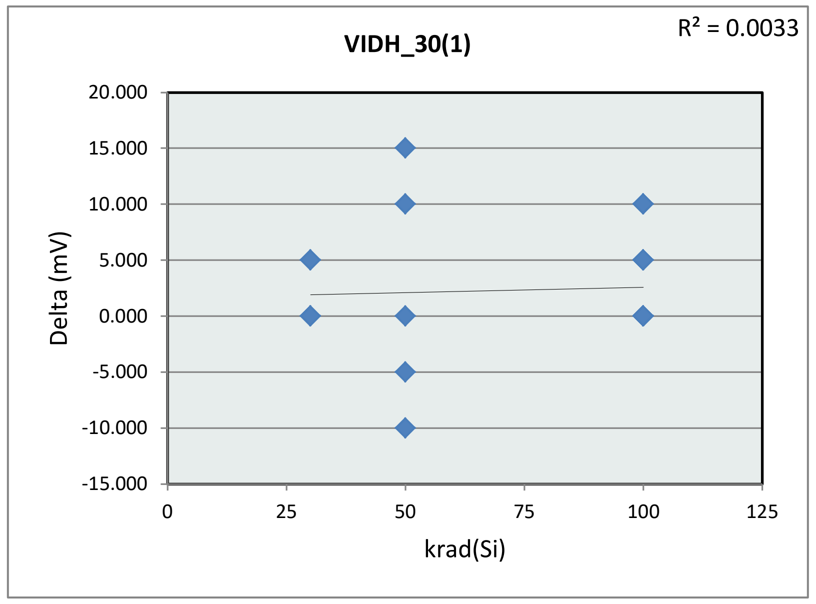


	DVOD_36(12)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	5.253	1.571	5.040
Average	9.671	9.180	9.682
Max	13.844	13.844	13.633
UL	25.000	25.000	25.000

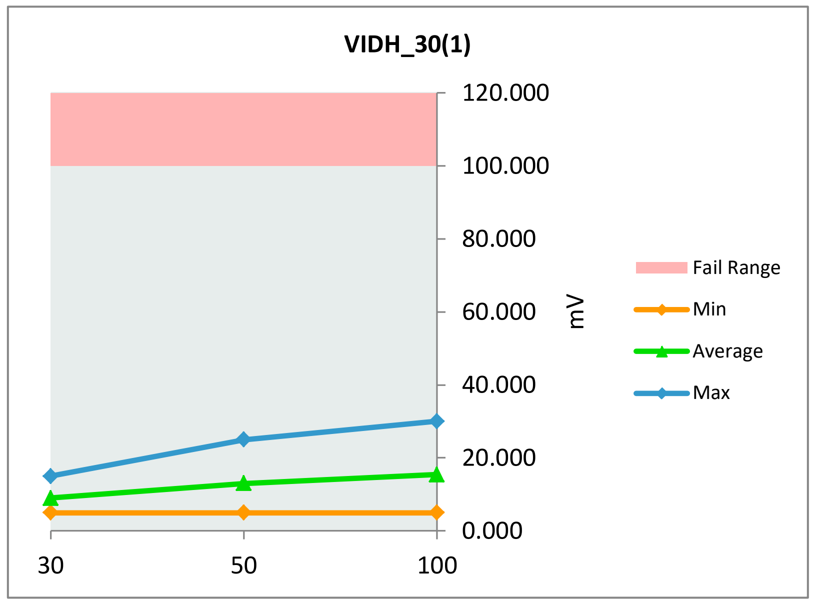


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	10.000	5.000	5.000
30	4	20.000	15.000	5.000
30	5	15.000	15.000	0.000
50	11	20.000	5.000	15.000
50	12	10.000	20.000	-10.000
50	13	20.000	10.000	10.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	25.000	25.000	0.000
100	24	20.000	20.000	0.000
100	25	30.000	30.000	0.000
100	26	30.000	30.000	0.000
100	27	20.000	20.000	0.000
100	28	5.000	5.000	0.000
100	29	15.000	5.000	10.000
100	30	25.000	20.000	5.000
100	31	5.000	5.000	0.000
100	32	20.000	15.000	5.000
100	33	25.000	20.000	5.000
100	34	30.000	30.000	0.000
100	35	15.000	15.000	0.000
100	36	5.000	5.000	0.000
100	37	20.000	20.000	0.000
100	38	20.000	20.000	0.000
100	39	15.000	5.000	10.000
100	40	25.000	20.000	5.000
100	41	15.000	5.000	10.000
100	42	5.000	5.000	0.000
100	43	20.000	15.000	5.000
100	44	20.000	15.000	5.000
	Max	30.000	30.000	15.000
	Average	16.515	14.091	2.424
	Min	5.000	5.000	-10.000
	Std Dev	8.148	8.611	4.861

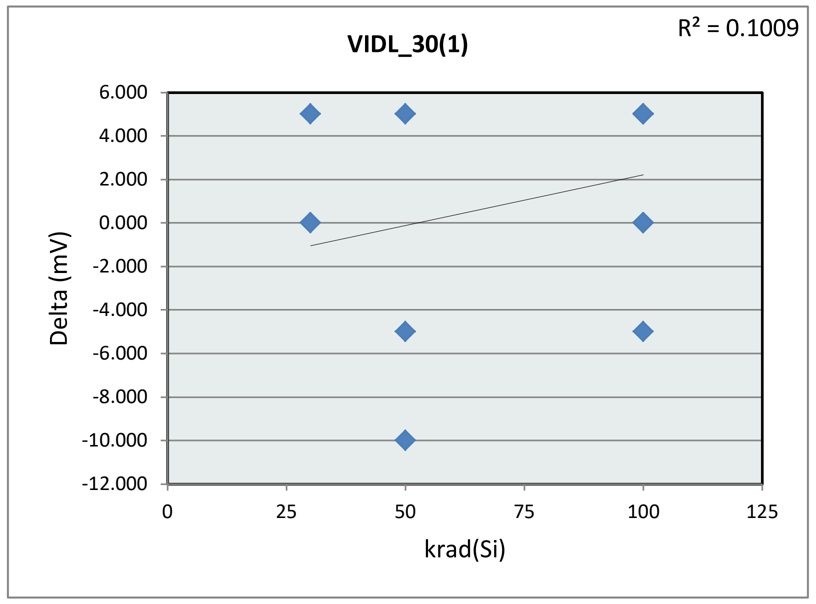


	VIDH_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	9.000	13.000	15.435
Max	15.000	25.000	30.000
UL	100.000	100.000	100.000

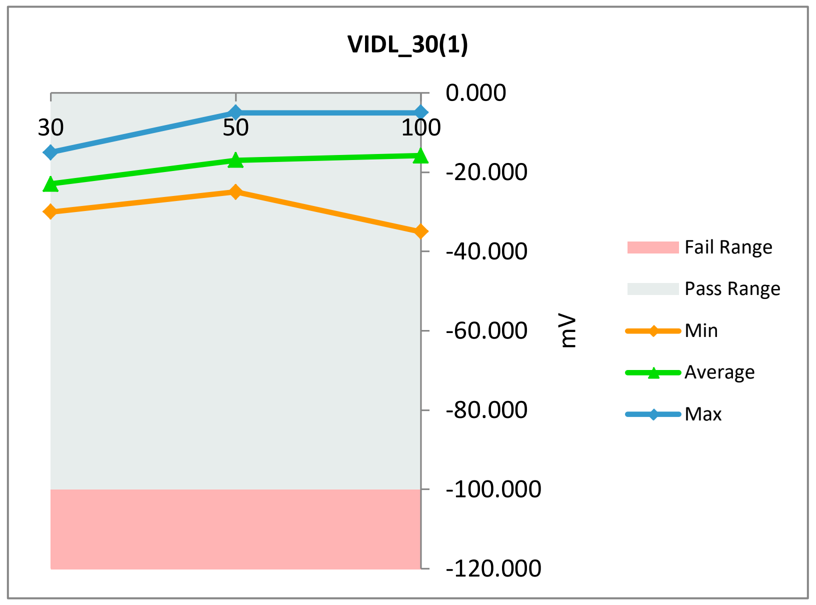


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-25.000	-25.000	0.000
30	2	-15.000	-15.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-15.000	-20.000	5.000
30	5	-25.000	-25.000	0.000
50	11	-15.000	-20.000	5.000
50	12	-25.000	-15.000	-10.000
50	13	-20.000	-25.000	5.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-15.000	-15.000	0.000
100	23	-10.000	-15.000	5.000
100	24	-5.000	-5.000	0.000
100	25	-20.000	-20.000	0.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-35.000	5.000
100	28	-30.000	-35.000	5.000
100	29	-15.000	-15.000	0.000
100	30	-5.000	-10.000	5.000
100	31	-25.000	-25.000	0.000
100	32	-15.000	-10.000	-5.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-10.000	5.000
100	35	-20.000	-25.000	5.000
100	36	-25.000	-30.000	5.000
100	37	-25.000	-25.000	0.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-10.000	5.000
100	40	-15.000	-15.000	0.000
100	41	-5.000	-10.000	5.000
100	42	-15.000	-20.000	5.000
100	43	-5.000	-10.000	5.000
100	44	-5.000	-10.000	5.000
	Max	-5.000	-5.000	5.000
	Average	-15.758	-17.121	1.364
	Min	-30.000	-35.000	-10.000
	Std Dev	9.024	8.842	4.197

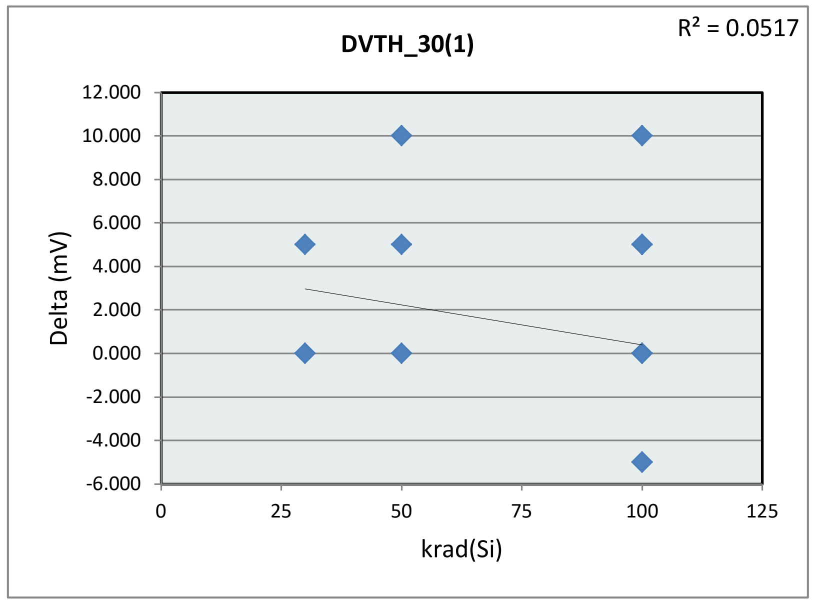


	VIDL_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-25.000	-35.000
Average	-23.000	-17.000	-15.870
Max	-15.000	-5.000	-5.000
UL			

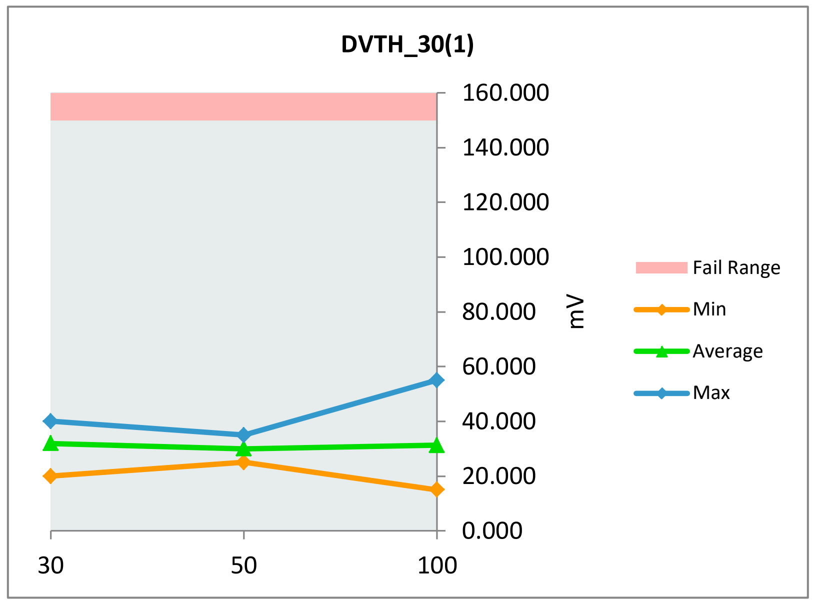


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	30.000	30.000	0.000
30	2	20.000	20.000	0.000
30	3	40.000	35.000	5.000
30	4	35.000	35.000	0.000
30	5	40.000	40.000	0.000
50	11	35.000	25.000	10.000
50	12	35.000	35.000	0.000
50	13	40.000	35.000	5.000
50	14	30.000	30.000	0.000
50	15	35.000	25.000	10.000
100	22	20.000	20.000	0.000
100	23	35.000	40.000	-5.000
100	24	25.000	25.000	0.000
100	25	50.000	50.000	0.000
100	26	35.000	35.000	0.000
100	27	50.000	55.000	-5.000
100	28	35.000	40.000	-5.000
100	29	30.000	20.000	10.000
100	30	30.000	30.000	0.000
100	31	30.000	30.000	0.000
100	32	35.000	25.000	10.000
100	33	30.000	25.000	5.000
100	34	35.000	40.000	-5.000
100	35	35.000	40.000	-5.000
100	36	30.000	35.000	-5.000
100	37	45.000	45.000	0.000
100	38	25.000	25.000	0.000
100	39	20.000	15.000	5.000
100	40	40.000	35.000	5.000
100	41	20.000	15.000	5.000
100	42	20.000	25.000	-5.000
100	43	25.000	25.000	0.000
100	44	25.000	25.000	0.000
	Max	50.000	55.000	10.000
	Average	32.273	31.212	1.061
	Min	20.000	15.000	-5.000
	Std Dev	8.110	9.440	4.636

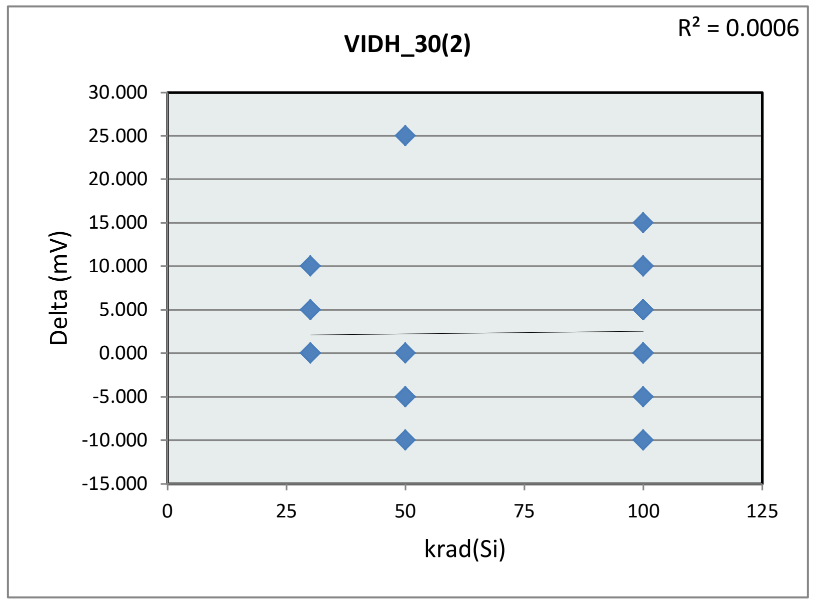


	DVTH_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	20.000	25.000	15.000
Average	32.000	30.000	31.304
Max	40.000	35.000	55.000
UL	150.000	150.000	150.000

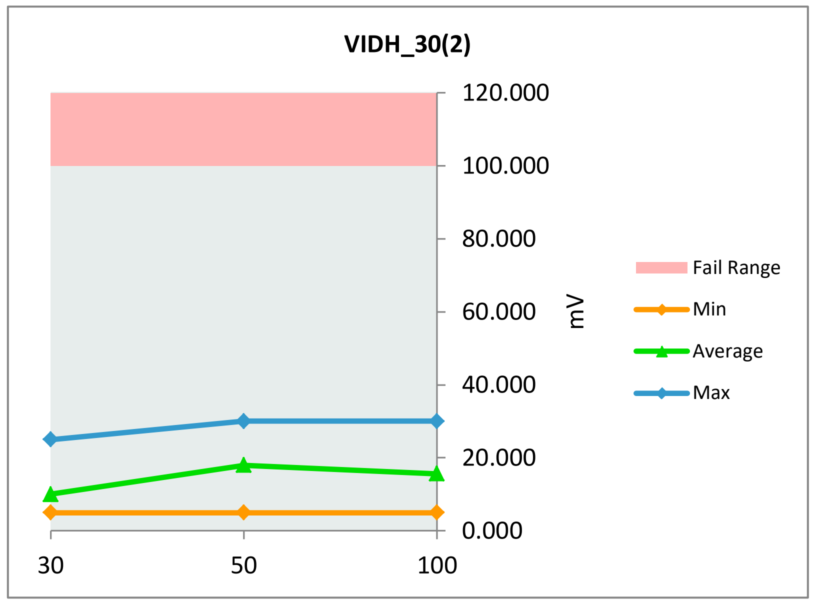


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	15.000	5.000	10.000
30	2	25.000	25.000	0.000
30	3	15.000	10.000	5.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	25.000	30.000	-5.000
50	13	15.000	25.000	-10.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	15.000	15.000	0.000
100	23	25.000	20.000	5.000
100	24	15.000	5.000	10.000
100	25	5.000	5.000	0.000
100	26	20.000	15.000	5.000
100	27	30.000	30.000	0.000
100	28	15.000	15.000	0.000
100	29	20.000	20.000	0.000
100	30	20.000	5.000	15.000
100	31	20.000	15.000	5.000
100	32	25.000	20.000	5.000
100	33	25.000	20.000	5.000
100	34	20.000	25.000	-5.000
100	35	25.000	25.000	0.000
100	36	10.000	5.000	5.000
100	37	25.000	25.000	0.000
100	38	15.000	5.000	10.000
100	39	20.000	15.000	5.000
100	40	5.000	5.000	0.000
100	41	20.000	15.000	5.000
100	42	15.000	5.000	10.000
100	43	15.000	25.000	-10.000
100	44	15.000	25.000	-10.000
	Max	30.000	30.000	25.000
	Average	17.576	15.152	2.424
	Min	5.000	5.000	-10.000
	Std Dev	7.194	8.969	7.194

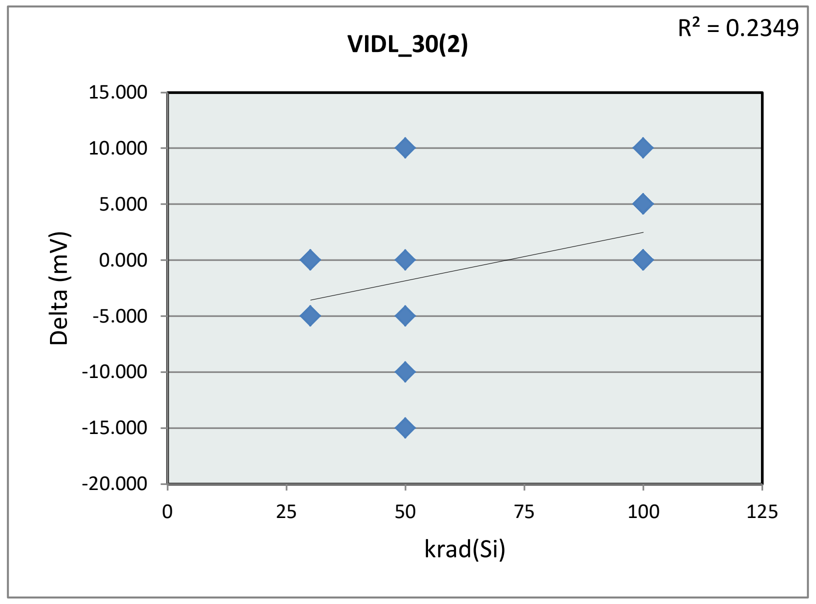


	VIDH_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	10.000	18.000	15.652
Max	25.000	30.000	30.000
UL	100.000	100.000	100.000

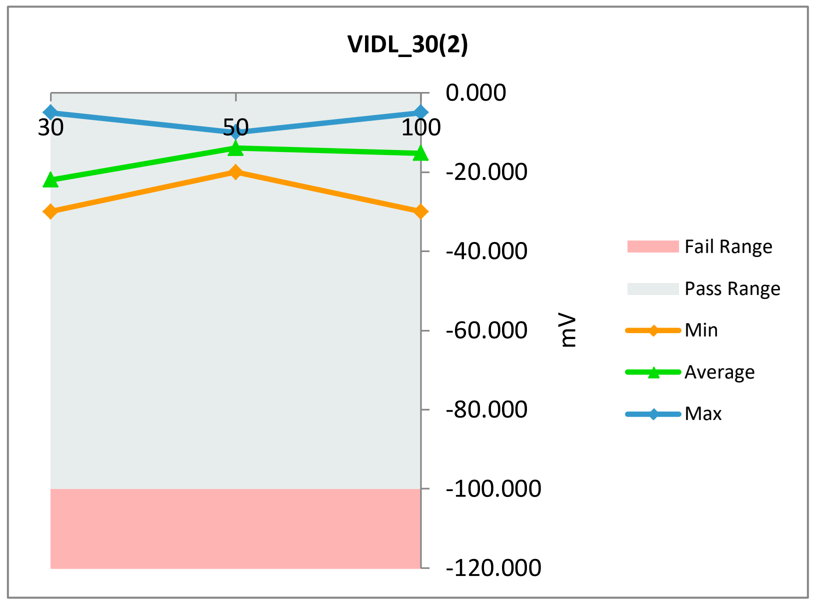


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-25.000	-20.000	-5.000
30	2	-5.000	-5.000	0.000
30	3	-35.000	-30.000	-5.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-10.000	0.000
50	13	-25.000	-10.000	-15.000
50	14	-15.000	-10.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-5.000	-10.000	5.000
100	23	-15.000	-15.000	0.000
100	24	-10.000	-15.000	5.000
100	25	-25.000	-25.000	0.000
100	26	-15.000	-15.000	0.000
100	27	-20.000	-30.000	10.000
100	28	-20.000	-25.000	5.000
100	29	-10.000	-10.000	0.000
100	30	-10.000	-10.000	0.000
100	31	-15.000	-15.000	0.000
100	32	-10.000	-10.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-20.000	5.000
100	35	-10.000	-15.000	5.000
100	36	-20.000	-25.000	5.000
100	37	-15.000	-20.000	5.000
100	38	-15.000	-20.000	5.000
100	39	-5.000	-5.000	0.000
100	40	-20.000	-20.000	0.000
100	41	-5.000	-10.000	5.000
100	42	-15.000	-20.000	5.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-15.152	-16.061	0.909
	Min	-35.000	-30.000	-15.000
	Std Dev	8.337	7.782	5.071

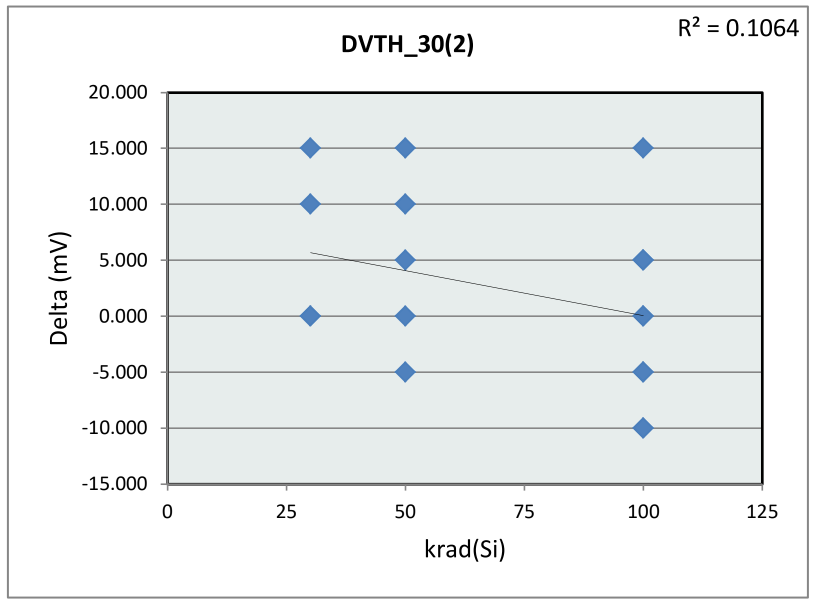


	VIDL_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-20.000	-30.000
Average	-22.000	-14.000	-15.217
Max	-5.000	-10.000	-5.000
UL			

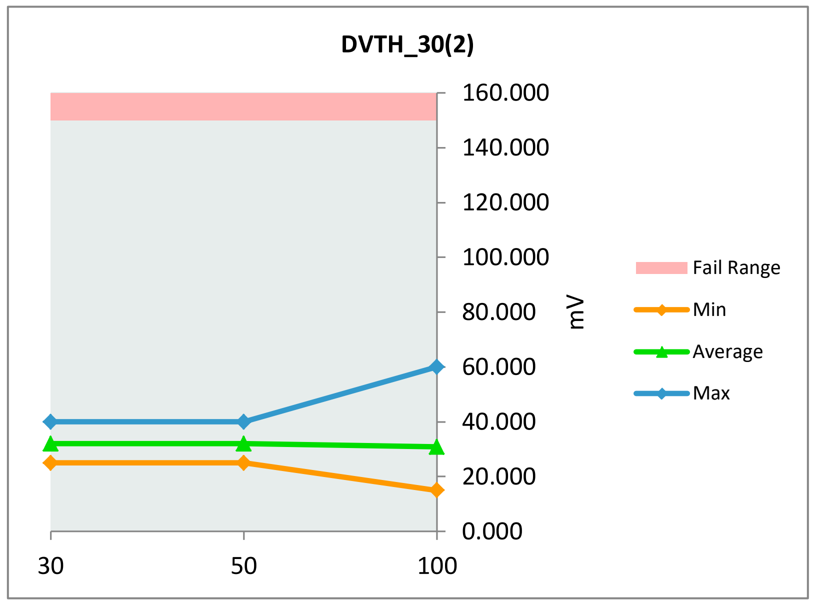


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	40.000	25.000	15.000
30	2	30.000	30.000	0.000
30	3	50.000	40.000	10.000
30	4	30.000	30.000	0.000
30	5	35.000	35.000	0.000
50	11	40.000	25.000	15.000
50	12	35.000	40.000	-5.000
50	13	40.000	35.000	5.000
50	14	35.000	35.000	0.000
50	15	35.000	25.000	10.000
100	22	20.000	25.000	-5.000
100	23	40.000	35.000	5.000
100	24	25.000	20.000	5.000
100	25	30.000	30.000	0.000
100	26	35.000	30.000	5.000
100	27	50.000	60.000	-10.000
100	28	35.000	40.000	-5.000
100	29	30.000	30.000	0.000
100	30	30.000	15.000	15.000
100	31	35.000	30.000	5.000
100	32	35.000	30.000	5.000
100	33	30.000	25.000	5.000
100	34	35.000	45.000	-10.000
100	35	35.000	40.000	-5.000
100	36	30.000	30.000	0.000
100	37	40.000	45.000	-5.000
100	38	30.000	25.000	5.000
100	39	25.000	20.000	5.000
100	40	25.000	25.000	0.000
100	41	25.000	25.000	0.000
100	42	30.000	25.000	5.000
100	43	20.000	30.000	-10.000
100	44	20.000	30.000	-10.000
	Max	50.000	60.000	15.000
	Average	32.727	31.212	1.515
	Min	20.000	15.000	-10.000
	Std Dev	7.298	8.753	7.014

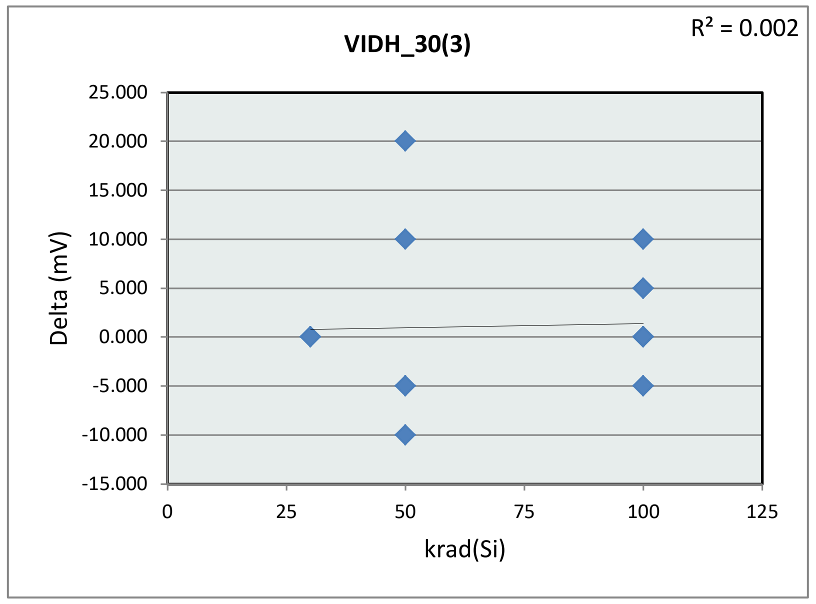


	DVTH_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	25.000	25.000	15.000
Average	32.000	32.000	30.870
Max	40.000	40.000	60.000
UL	150.000	150.000	150.000

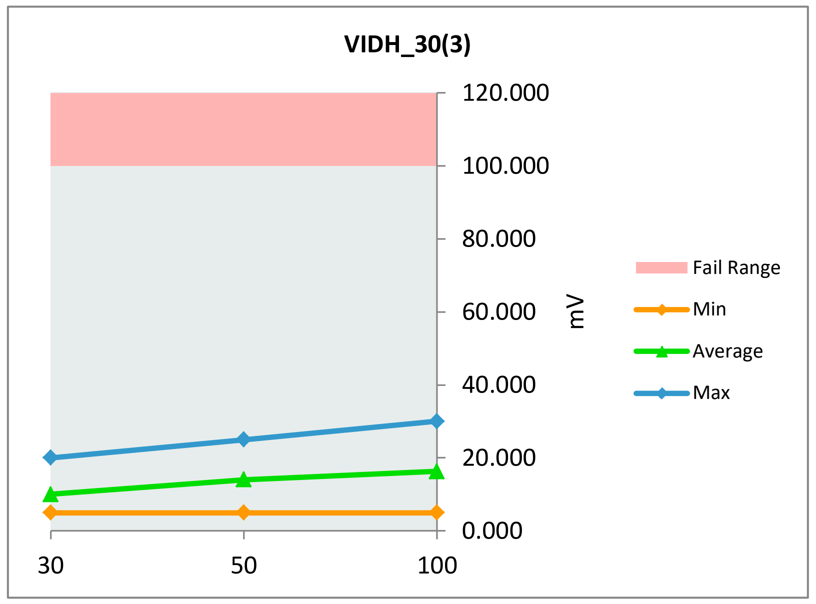


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	5.000	0.000
30	4	20.000	20.000	0.000
30	5	15.000	15.000	0.000
50	11	25.000	5.000	20.000
50	12	15.000	20.000	-5.000
50	13	15.000	5.000	10.000
50	14	20.000	25.000	-5.000
50	15	5.000	15.000	-10.000
100	22	5.000	5.000	0.000
100	23	25.000	25.000	0.000
100	24	20.000	20.000	0.000
100	25	30.000	30.000	0.000
100	26	35.000	30.000	5.000
100	27	20.000	20.000	0.000
100	28	5.000	5.000	0.000
100	29	15.000	5.000	10.000
100	30	25.000	20.000	5.000
100	31	5.000	5.000	0.000
100	32	20.000	15.000	5.000
100	33	25.000	20.000	5.000
100	34	30.000	30.000	0.000
100	35	15.000	20.000	-5.000
100	36	5.000	5.000	0.000
100	37	20.000	20.000	0.000
100	38	20.000	20.000	0.000
100	39	15.000	5.000	10.000
100	40	20.000	20.000	0.000
100	41	15.000	10.000	5.000
100	42	5.000	5.000	0.000
100	43	15.000	20.000	-5.000
100	44	15.000	20.000	-5.000
	Max	35.000	30.000	20.000
	Average	16.212	15.000	1.212
	Min	5.000	5.000	-10.000
	Std Dev	8.481	8.660	5.594

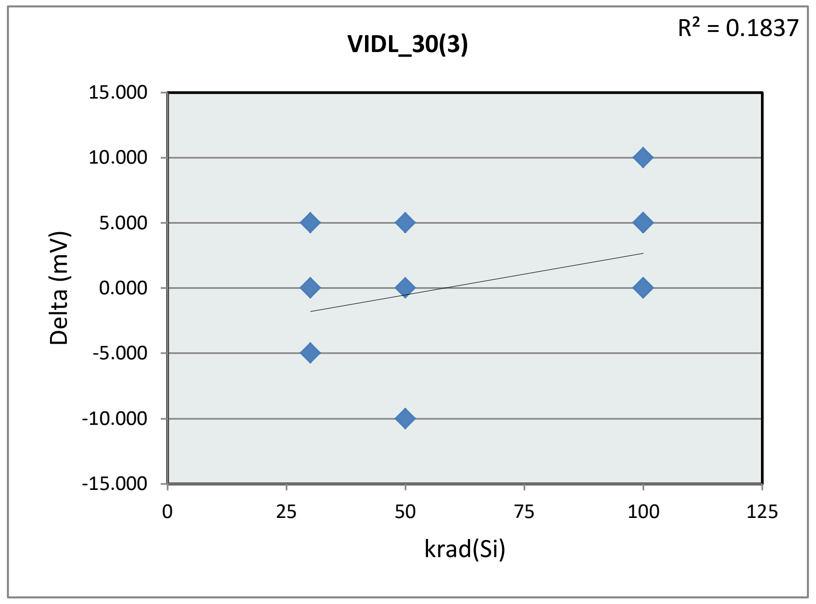


	VIDH_30(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	10.000	14.000	16.304
Max	20.000	25.000	30.000
UL	100.000	100.000	100.000

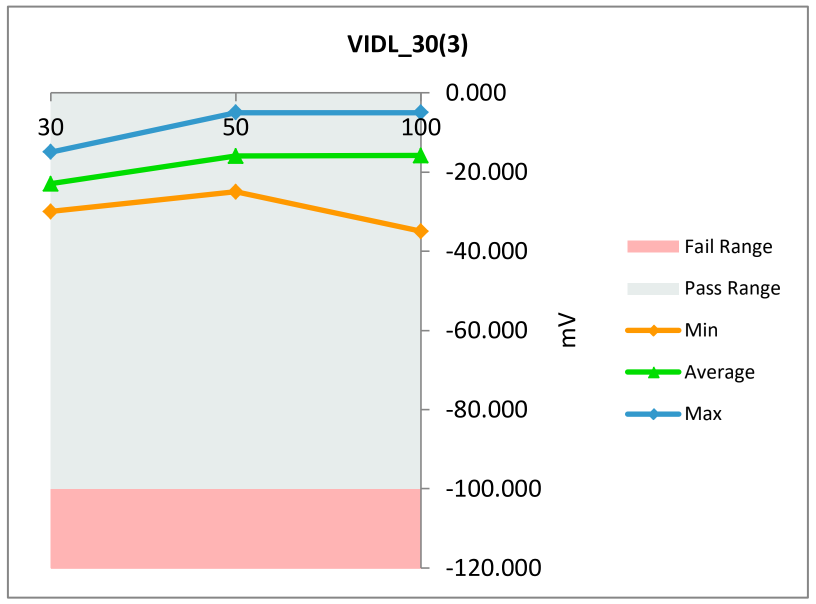


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-30.000	-30.000	0.000
30	2	-15.000	-15.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-20.000	-15.000	-5.000
30	5	-20.000	-25.000	5.000
50	11	-15.000	-15.000	0.000
50	12	-25.000	-15.000	-10.000
50	13	-20.000	-25.000	5.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-20.000	-10.000
100	22	-15.000	-15.000	0.000
100	23	-5.000	-15.000	10.000
100	24	-5.000	-10.000	5.000
100	25	-20.000	-20.000	0.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-35.000	5.000
100	28	-30.000	-35.000	5.000
100	29	-15.000	-15.000	0.000
100	30	-5.000	-10.000	5.000
100	31	-25.000	-25.000	0.000
100	32	-15.000	-15.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-25.000	5.000
100	36	-25.000	-30.000	5.000
100	37	-25.000	-25.000	0.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-10.000	5.000
100	40	-10.000	-15.000	5.000
100	41	-5.000	-5.000	0.000
100	42	-15.000	-20.000	5.000
100	43	-5.000	-10.000	5.000
100	44	-5.000	-10.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-15.455	-16.970	1.515
	Min	-30.000	-35.000	-10.000
	Std Dev	9.467	9.095	4.236

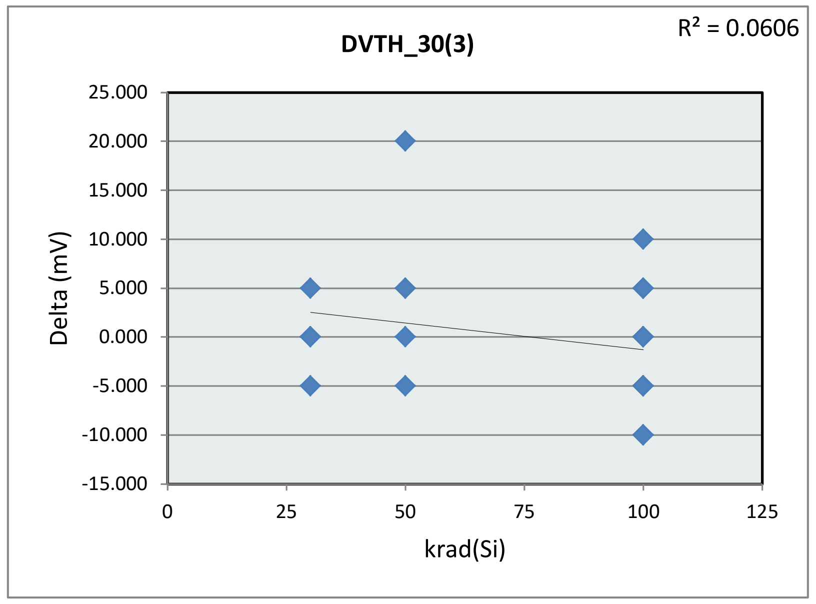


	VIDL_30(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-25.000	-35.000
Average	-23.000	-16.000	-15.870
Max	-15.000	-5.000	-5.000
UL			

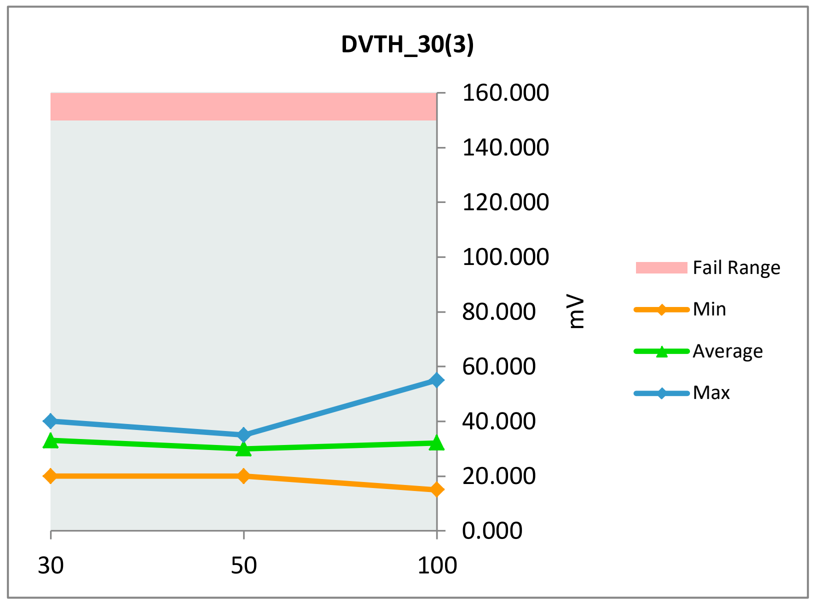


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	35.000	35.000	0.000
30	2	20.000	20.000	0.000
30	3	35.000	35.000	0.000
30	4	40.000	35.000	5.000
30	5	35.000	40.000	-5.000
50	11	40.000	20.000	20.000
50	12	40.000	35.000	5.000
50	13	35.000	30.000	5.000
50	14	25.000	30.000	-5.000
50	15	35.000	35.000	0.000
100	22	20.000	20.000	0.000
100	23	30.000	40.000	-10.000
100	24	25.000	30.000	-5.000
100	25	50.000	50.000	0.000
100	26	40.000	35.000	5.000
100	27	50.000	55.000	-5.000
100	28	35.000	40.000	-5.000
100	29	30.000	20.000	10.000
100	30	30.000	30.000	0.000
100	31	30.000	30.000	0.000
100	32	35.000	30.000	5.000
100	33	30.000	25.000	5.000
100	34	35.000	35.000	0.000
100	35	35.000	45.000	-10.000
100	36	30.000	35.000	-5.000
100	37	45.000	45.000	0.000
100	38	25.000	25.000	0.000
100	39	20.000	15.000	5.000
100	40	30.000	35.000	-5.000
100	41	20.000	15.000	5.000
100	42	20.000	25.000	-5.000
100	43	20.000	30.000	-10.000
100	44	20.000	30.000	-10.000
	Max	50.000	55.000	20.000
	Average	31.667	31.970	-0.303
	Min	20.000	15.000	-10.000
	Std Dev	8.539	9.349	6.366



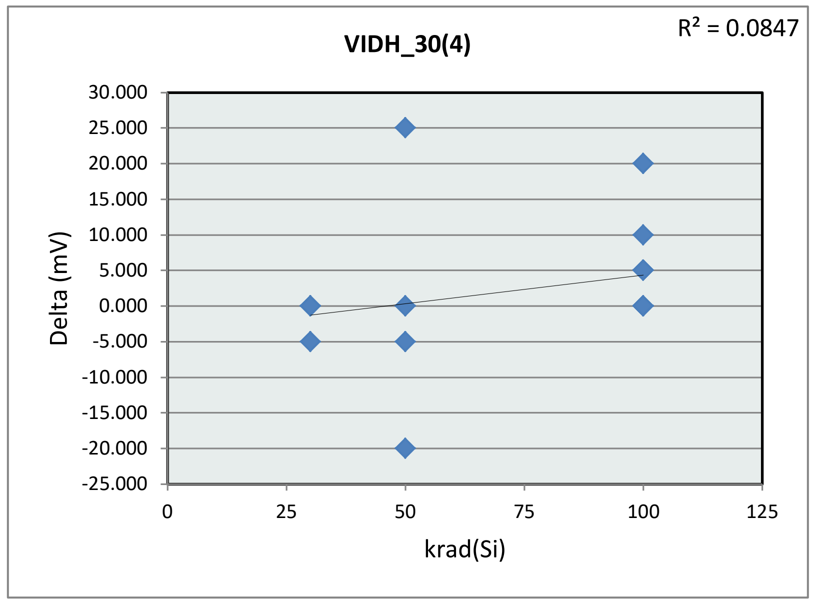
	DVTH_30(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	20.000	20.000	15.000
Average	33.000	30.000	32.174
Max	40.000	35.000	55.000
UL	150.000	150.000	150.000



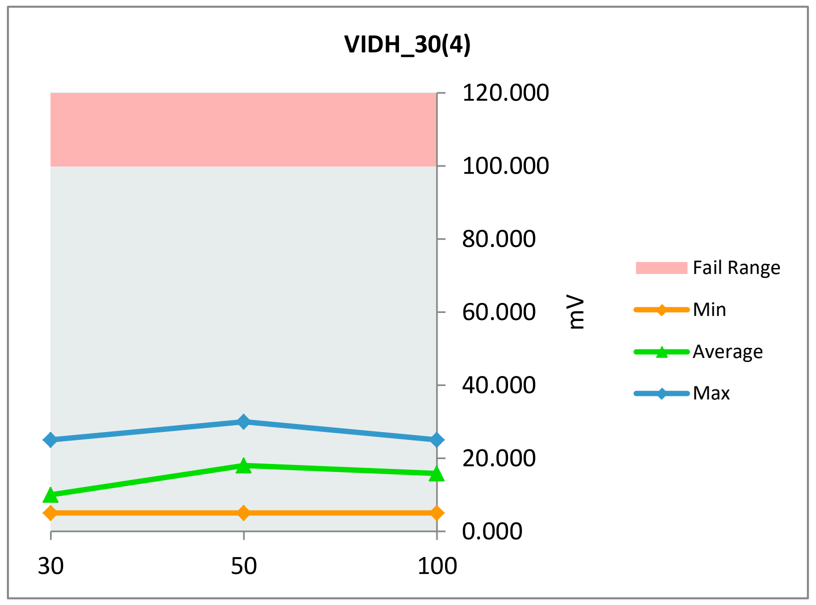
HDR TID Report T0 data
SN55LVCP22A-SP

	VIDH_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	25.000	25.000	0.000
30	3	5.000	10.000	-5.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	30.000	30.000	0.000
50	13	5.000	25.000	-20.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	20.000	20.000	0.000
100	23	25.000	5.000	20.000
100	24	20.000	15.000	5.000
100	25	25.000	5.000	20.000
100	26	20.000	20.000	0.000
100	27	25.000	25.000	0.000
100	28	20.000	15.000	5.000
100	29	20.000	15.000	5.000
100	30	20.000	20.000	0.000
100	31	15.000	15.000	0.000
100	32	25.000	20.000	5.000
100	33	25.000	20.000	5.000
100	34	25.000	25.000	0.000
100	35	25.000	25.000	0.000
100	36	10.000	5.000	5.000
100	37	25.000	20.000	5.000
100	38	15.000	5.000	10.000
100	39	20.000	15.000	5.000
100	40	5.000	5.000	0.000
100	41	20.000	15.000	5.000
100	42	10.000	5.000	5.000
100	43	25.000	25.000	0.000
100	44	25.000	25.000	0.000
	Max	30.000	30.000	25.000
	Average	18.182	15.303	2.879
	Min	5.000	5.000	-20.000
	Std Dev	8.274	8.472	7.809

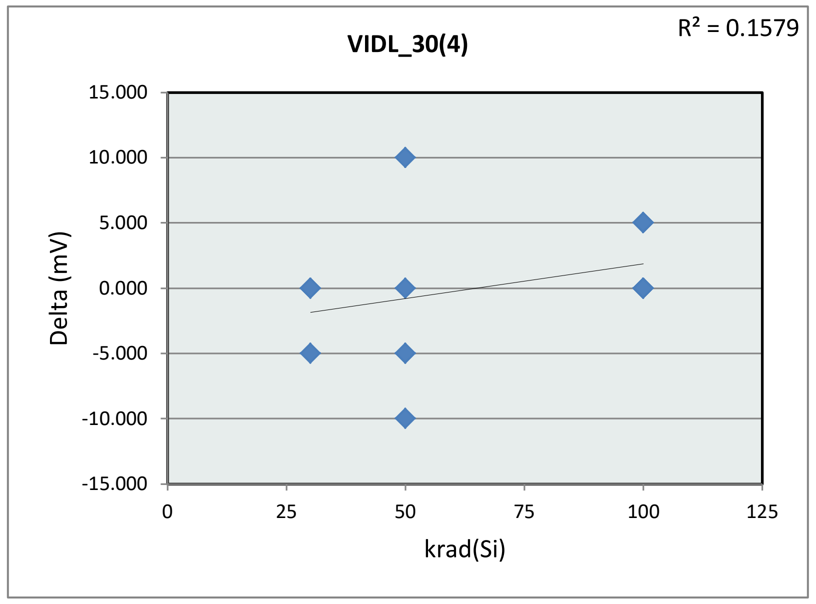


	VIDH_30(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	10.000	18.000	15.870
Max	25.000	30.000	25.000
UL	100.000	100.000	100.000

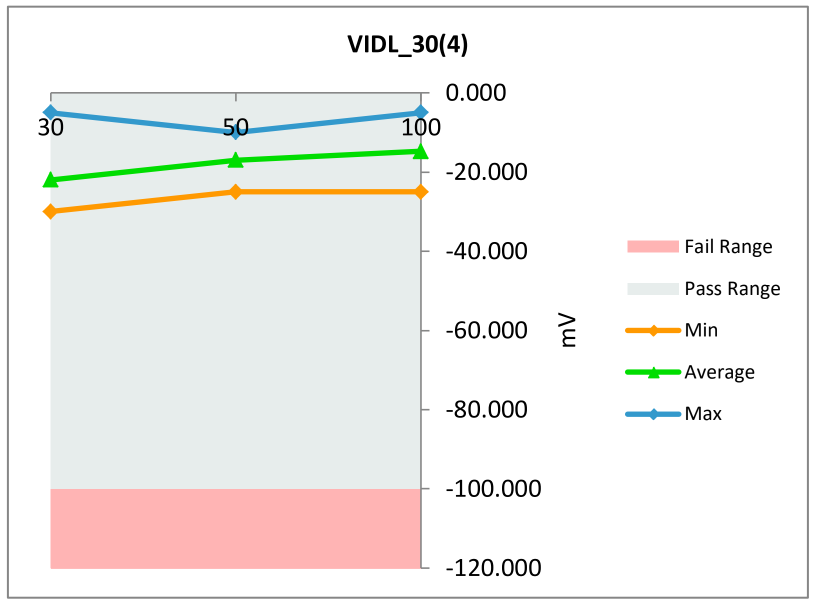


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-20.000	-20.000	0.000
30	2	-5.000	-5.000	0.000
30	3	-35.000	-30.000	-5.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-15.000	-25.000	10.000
50	12	-15.000	-10.000	-5.000
50	13	-25.000	-15.000	-10.000
50	14	-10.000	-10.000	0.000
50	15	-30.000	-25.000	-5.000
100	22	-10.000	-10.000	0.000
100	23	-15.000	-20.000	5.000
100	24	-10.000	-15.000	5.000
100	25	-25.000	-25.000	0.000
100	26	-15.000	-15.000	0.000
100	27	-20.000	-25.000	5.000
100	28	-25.000	-25.000	0.000
100	29	-10.000	-15.000	5.000
100	30	-10.000	-10.000	0.000
100	31	-10.000	-15.000	5.000
100	32	-10.000	-10.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-15.000	0.000
100	35	-10.000	-15.000	5.000
100	36	-20.000	-20.000	0.000
100	37	-15.000	-20.000	5.000
100	38	-15.000	-20.000	5.000
100	39	-5.000	-5.000	0.000
100	40	-20.000	-25.000	5.000
100	41	-5.000	-5.000	0.000
100	42	-15.000	-15.000	0.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-15.303	-16.212	0.909
	Min	-35.000	-30.000	-10.000
	Std Dev	8.191	7.809	3.844

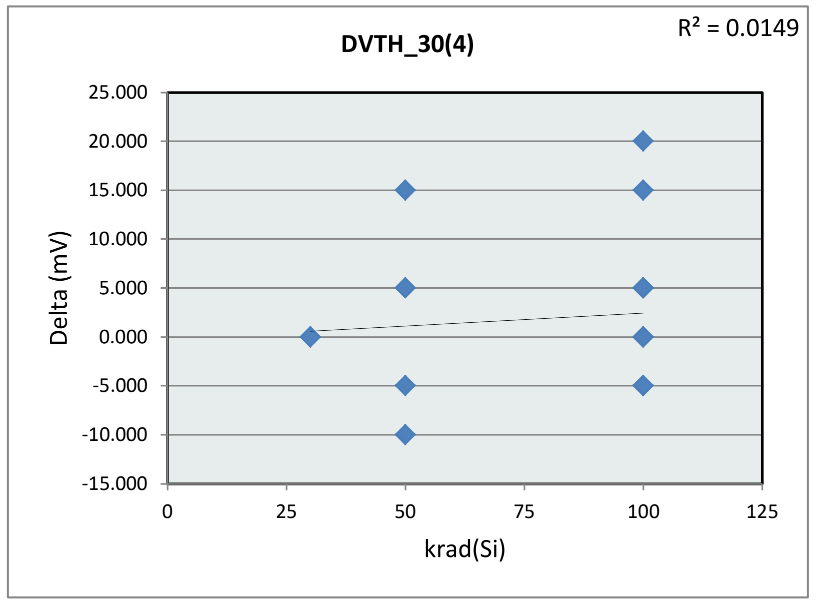


	VIDL_30(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-25.000	-25.000
Average	-22.000	-17.000	-14.783
Max	-5.000	-10.000	-5.000
UL			

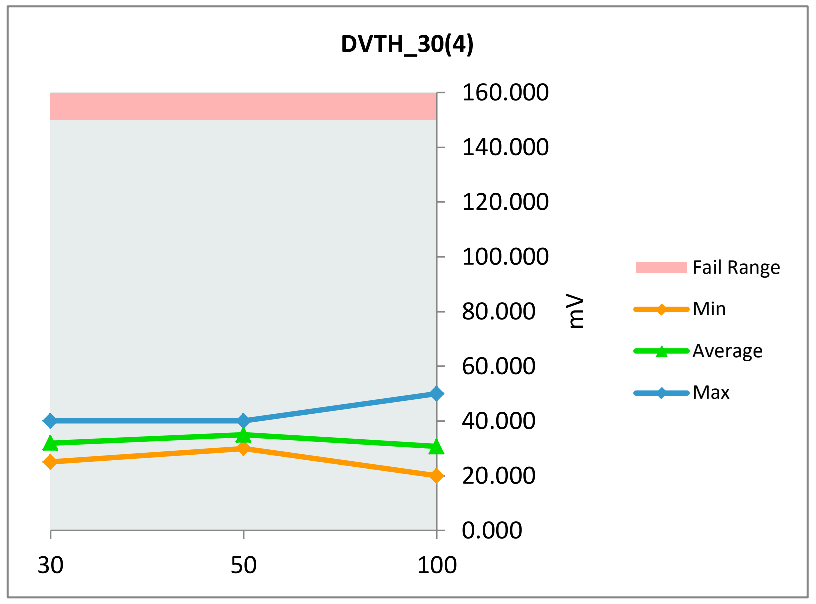


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	25.000	25.000	0.000
30	2	30.000	30.000	0.000
30	3	40.000	40.000	0.000
30	4	30.000	30.000	0.000
30	5	35.000	35.000	0.000
50	11	45.000	30.000	15.000
50	12	45.000	40.000	5.000
50	13	30.000	40.000	-10.000
50	14	30.000	35.000	-5.000
50	15	35.000	30.000	5.000
100	22	30.000	30.000	0.000
100	23	40.000	25.000	15.000
100	24	30.000	30.000	0.000
100	25	50.000	30.000	20.000
100	26	35.000	35.000	0.000
100	27	45.000	50.000	-5.000
100	28	45.000	40.000	5.000
100	29	30.000	30.000	0.000
100	30	30.000	30.000	0.000
100	31	25.000	30.000	-5.000
100	32	35.000	30.000	5.000
100	33	30.000	25.000	5.000
100	34	40.000	40.000	0.000
100	35	35.000	40.000	-5.000
100	36	30.000	25.000	5.000
100	37	40.000	40.000	0.000
100	38	30.000	25.000	5.000
100	39	25.000	20.000	5.000
100	40	25.000	30.000	-5.000
100	41	25.000	20.000	5.000
100	42	25.000	20.000	5.000
100	43	30.000	30.000	0.000
100	44	30.000	30.000	0.000
	Max	50.000	50.000	20.000
	Average	33.485	31.515	1.970
	Min	25.000	20.000	-10.000
	Std Dev	7.014	6.902	6.116



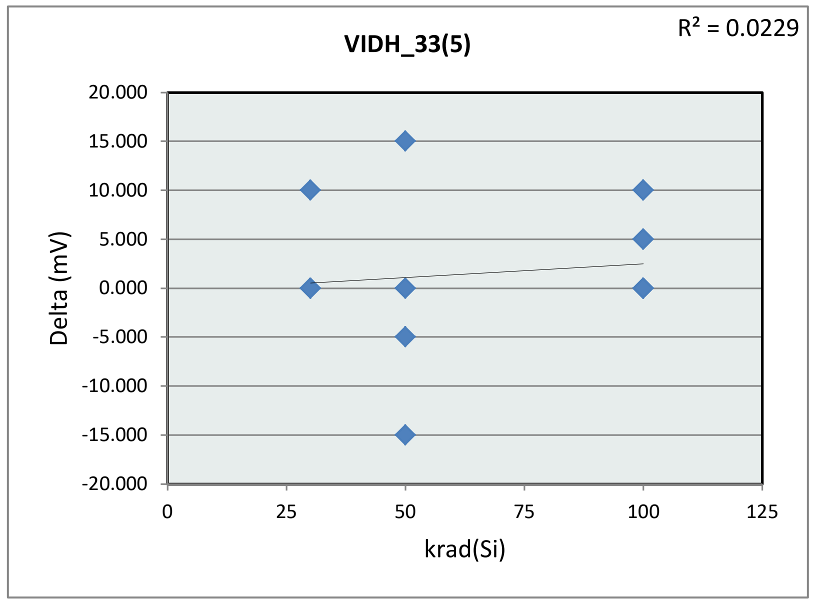
	DVTH_30(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	25.000	30.000	20.000
Average	32.000	35.000	30.652
Max	40.000	40.000	50.000
UL	150.000	150.000	150.000



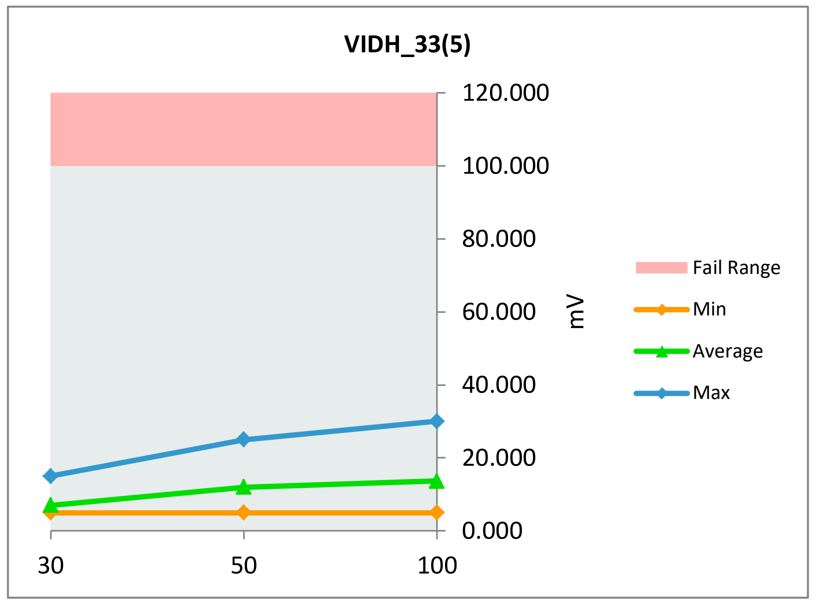
HDR TID Report T0 data
SN55LVCP22A-SP

	VIDH_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	5.000	0.000
30	4	15.000	15.000	0.000
30	5	15.000	5.000	10.000
50	11	20.000	5.000	15.000
50	12	5.000	20.000	-15.000
50	13	5.000	5.000	0.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	25.000	20.000	5.000
100	24	15.000	15.000	0.000
100	25	30.000	30.000	0.000
100	26	30.000	30.000	0.000
100	27	15.000	5.000	10.000
100	28	5.000	5.000	0.000
100	29	15.000	10.000	5.000
100	30	20.000	20.000	0.000
100	31	5.000	5.000	0.000
100	32	15.000	15.000	0.000
100	33	25.000	20.000	5.000
100	34	25.000	25.000	0.000
100	35	15.000	5.000	10.000
100	36	5.000	5.000	0.000
100	37	20.000	15.000	5.000
100	38	20.000	20.000	0.000
100	39	5.000	5.000	0.000
100	40	20.000	20.000	0.000
100	41	15.000	5.000	10.000
100	42	5.000	5.000	0.000
100	43	20.000	15.000	5.000
100	44	20.000	15.000	5.000
	Max	30.000	30.000	15.000
	Average	14.394	12.424	1.970
	Min	5.000	5.000	-15.000
	Std Dev	8.174	8.303	5.294

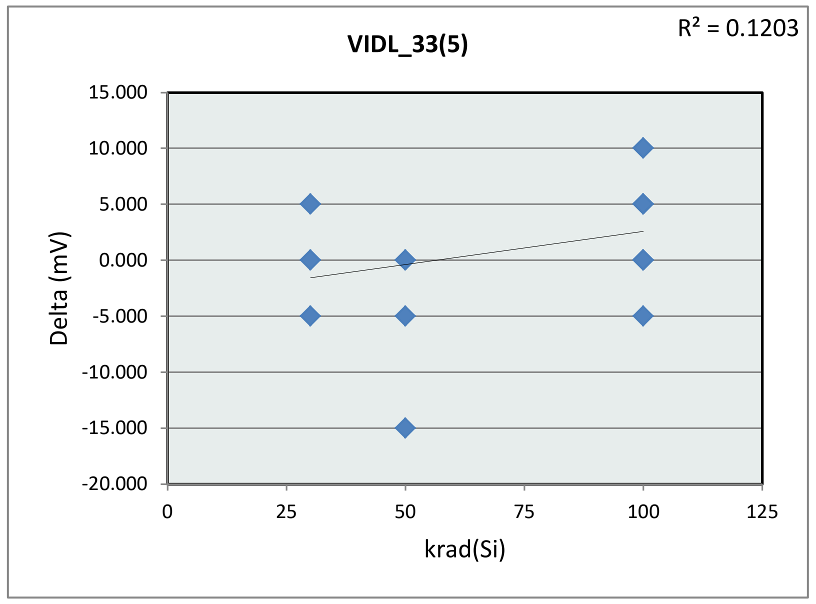


	VIDH_33(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	7.000	12.000	13.696
Max	15.000	25.000	30.000
UL	100.000	100.000	100.000

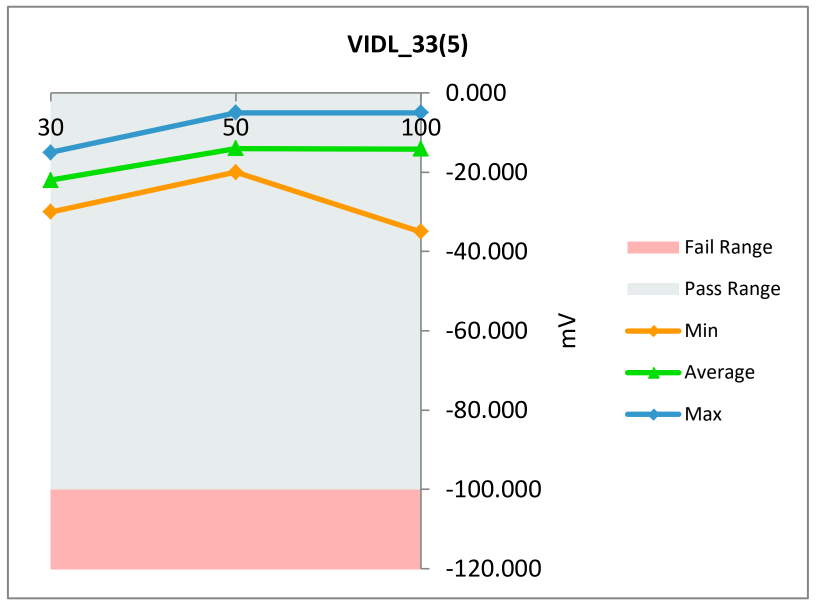


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-30.000	-30.000	0.000
30	2	-10.000	-15.000	5.000
30	3	-30.000	-25.000	-5.000
30	4	-15.000	-20.000	5.000
30	5	-20.000	-20.000	0.000
50	11	-15.000	-15.000	0.000
50	12	-20.000	-15.000	-5.000
50	13	-20.000	-20.000	0.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-15.000	-15.000
100	22	-5.000	-15.000	10.000
100	23	-5.000	-15.000	10.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-20.000	5.000
100	26	-5.000	-5.000	0.000
100	27	-35.000	-35.000	0.000
100	28	-30.000	-35.000	5.000
100	29	-5.000	-15.000	10.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-25.000	5.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-20.000	0.000
100	36	-25.000	-30.000	5.000
100	37	-20.000	-25.000	5.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	40	-10.000	-5.000	-5.000
100	41	-5.000	-5.000	0.000
100	42	-15.000	-20.000	5.000
100	43	-5.000	-10.000	5.000
100	44	-5.000	-10.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-13.788	-15.303	1.515
	Min	-35.000	-35.000	-15.000
	Std Dev	9.765	9.432	4.919



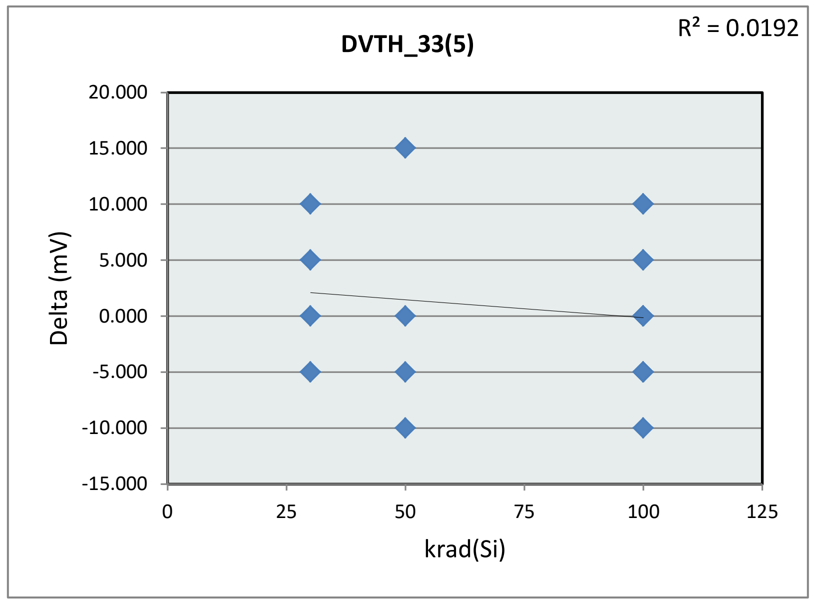
	VIDL_33(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-20.000	-35.000
Average	-22.000	-14.000	-14.130
Max	-15.000	-5.000	-5.000
UL			



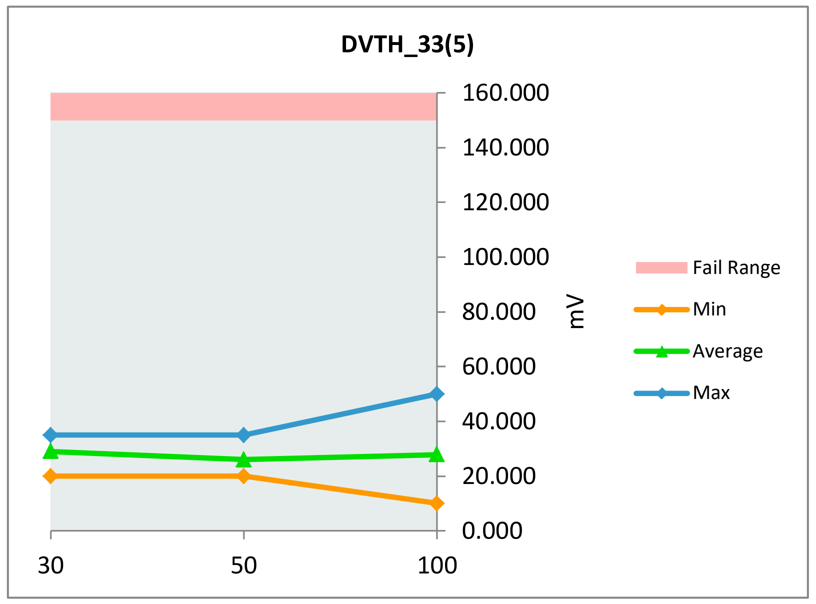
HDR TID Report T0 data
SN55LVCP22A-SP

	DVTH_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	35.000	35.000	0.000
30	2	15.000	20.000	-5.000
30	3	35.000	30.000	5.000
30	4	30.000	35.000	-5.000
30	5	35.000	25.000	10.000
50	11	35.000	20.000	15.000
50	12	25.000	35.000	-10.000
50	13	25.000	25.000	0.000
50	14	25.000	30.000	-5.000
50	15	35.000	20.000	15.000
100	22	10.000	20.000	-10.000
100	23	30.000	35.000	-5.000
100	24	20.000	20.000	0.000
100	25	45.000	50.000	-5.000
100	26	35.000	35.000	0.000
100	27	50.000	40.000	10.000
100	28	35.000	40.000	-5.000
100	29	20.000	25.000	-5.000
100	30	25.000	25.000	0.000
100	31	25.000	30.000	-5.000
100	32	20.000	20.000	0.000
100	33	30.000	25.000	5.000
100	34	30.000	30.000	0.000
100	35	35.000	25.000	10.000
100	36	30.000	35.000	-5.000
100	37	40.000	40.000	0.000
100	38	25.000	25.000	0.000
100	39	10.000	10.000	0.000
100	40	30.000	25.000	5.000
100	41	20.000	10.000	10.000
100	42	20.000	25.000	-5.000
100	43	25.000	25.000	0.000
100	44	25.000	25.000	0.000
	Max	50.000	50.000	15.000
	Average	28.182	27.727	0.455
	Min	10.000	10.000	-10.000
	Std Dev	8.911	8.578	6.539



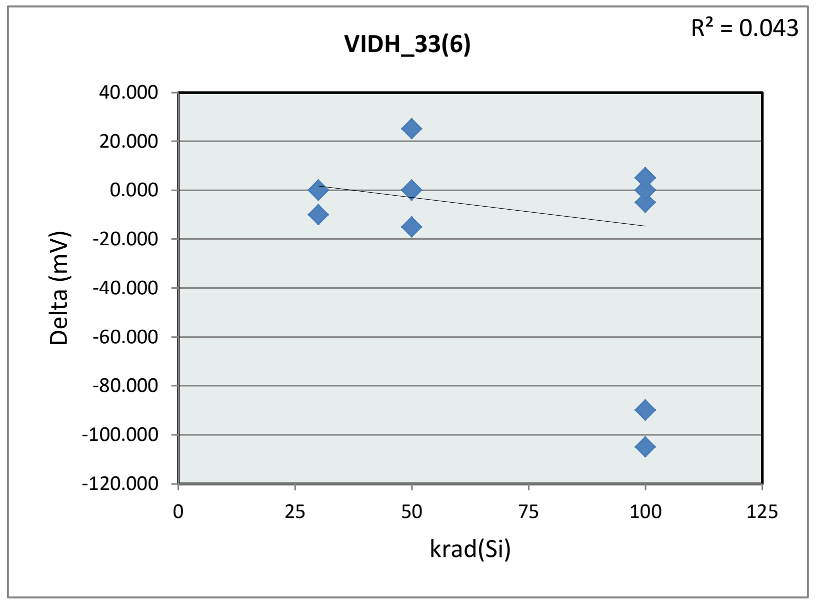
	DVTH_33(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	20.000	20.000	10.000
Average	29.000	26.000	27.826
Max	35.000	35.000	50.000
UL	150.000	150.000	150.000



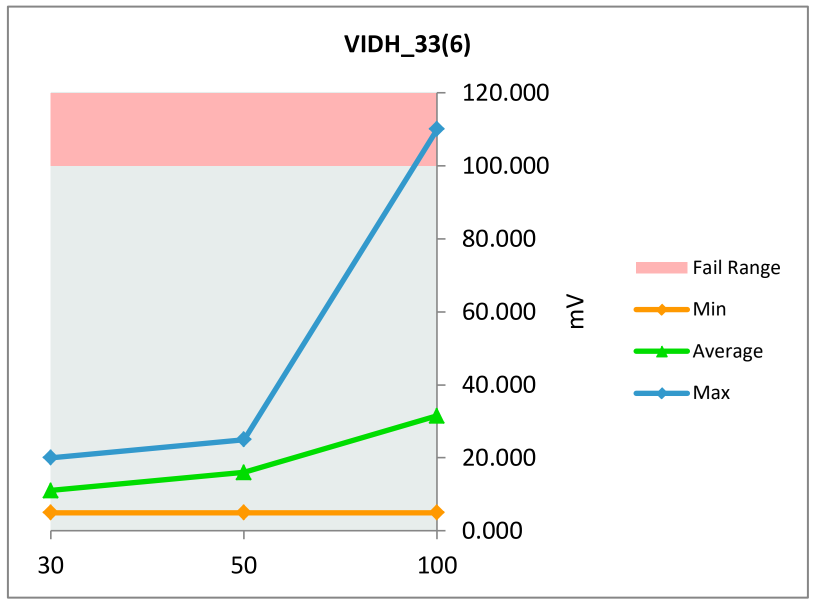
HDR TID Report T0 data
SN55LVCP22A-SP

	VIDH_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	10.000	10.000	0.000
30	2	20.000	20.000	0.000
30	3	5.000	5.000	0.000
30	4	5.000	15.000	-10.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	25.000	25.000	0.000
50	13	10.000	25.000	-15.000
50	14	20.000	20.000	0.000
50	15	5.000	5.000	0.000
100	22	15.000	15.000	0.000
100	23	20.000	20.000	0.000
100	24	15.000	15.000	0.000
100	25	5.000	10.000	-5.000
100	26	20.000	15.000	5.000
100	27	25.000	25.000	0.000
100	28	15.000	15.000	0.000
100	29	20.000	15.000	5.000
100	30	15.000	15.000	0.000
100	31	20.000	15.000	5.000
100	32	20.000	20.000	0.000
100	33	20.000	20.000	0.000
100	34	20.000	110.000	-90.000
100	35	20.000	110.000	-90.000
100	36	5.000	110.000	-105.000
100	37	20.000	110.000	-90.000
100	38	5.000	5.000	0.000
100	39	20.000	15.000	5.000
100	40	5.000	5.000	0.000
100	41	20.000	15.000	5.000
100	42	5.000	5.000	0.000
100	43	25.000	20.000	5.000
100	44	25.000	20.000	5.000
	Max	30.000	110.000	25.000
	Average	15.606	26.061	-10.455
	Min	5.000	5.000	-105.000
	Std Dev	7.681	32.253	32.049

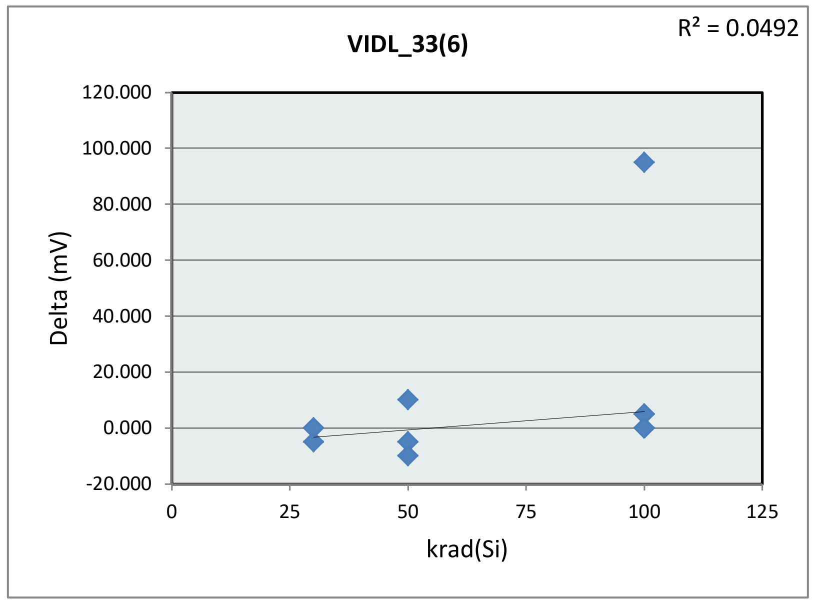


	VIDH_33(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	11.000	16.000	31.522
Max	20.000	25.000	110.000
UL	100.000	100.000	100.000

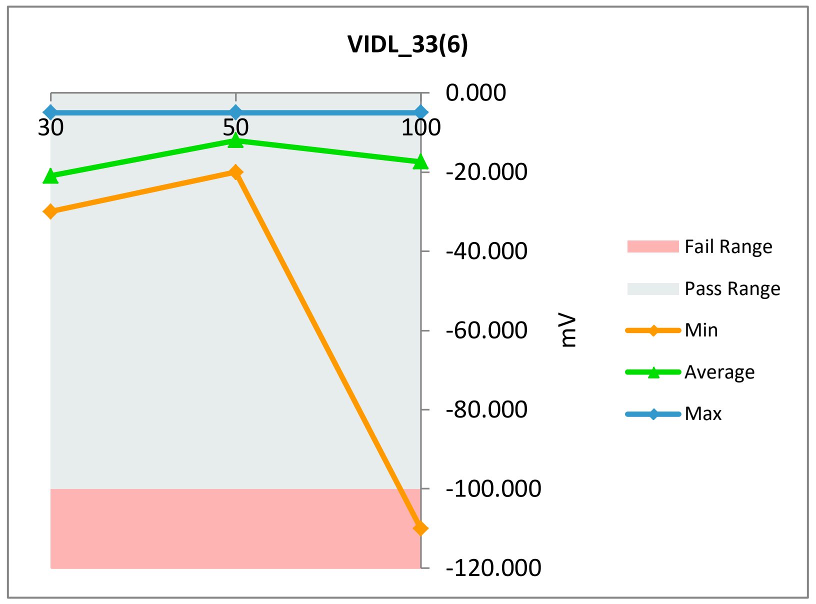


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-20.000	-15.000	-5.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-20.000	-10.000	-10.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-10.000	-10.000	0.000
100	23	-10.000	-15.000	5.000
100	24	-10.000	-10.000	0.000
100	25	-20.000	-25.000	5.000
100	26	-10.000	-15.000	5.000
100	27	-25.000	-25.000	0.000
100	28	-20.000	-25.000	5.000
100	29	-5.000	-10.000	5.000
100	30	-10.000	-10.000	0.000
100	31	-10.000	-10.000	0.000
100	32	-5.000	-10.000	5.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-110.000	95.000
100	35	-10.000	-10.000	0.000
100	36	-15.000	-20.000	5.000
100	37	-15.000	-15.000	0.000
100	38	-15.000	-15.000	0.000
100	39	-5.000	-5.000	0.000
100	40	-20.000	-20.000	0.000
100	41	-5.000	-10.000	5.000
100	42	-10.000	-15.000	5.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	95.000
	Average	-13.636	-17.121	3.485
	Min	-30.000	-110.000	-10.000
	Std Dev	7.933	18.330	16.978

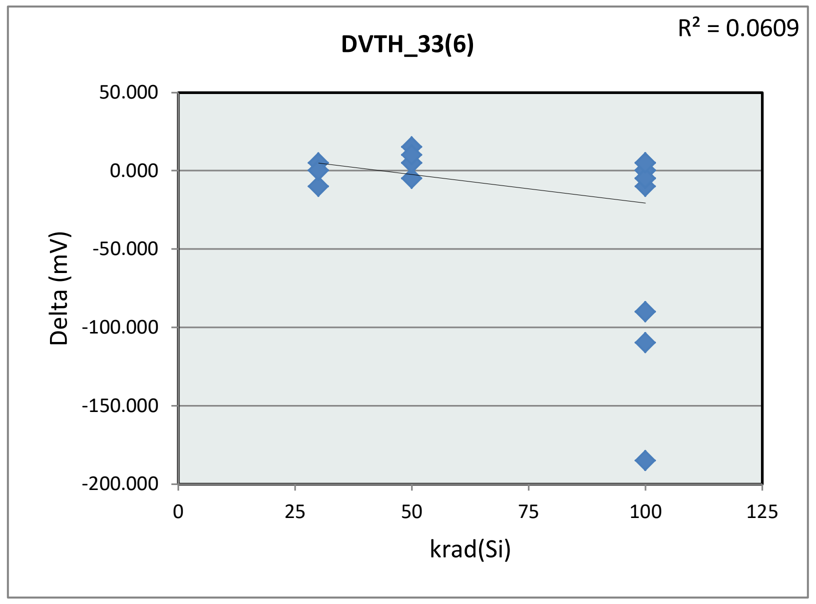


	VIDL_33(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-20.000	-110.000
Average	-21.000	-12.000	-17.391
Max	-5.000	-5.000	-5.000
UL			

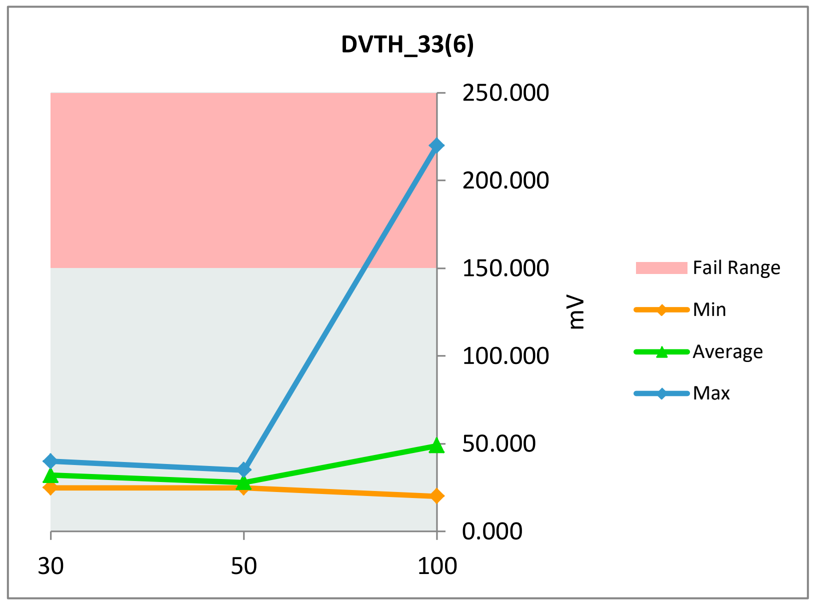


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	30.000	25.000	5.000
30	2	25.000	25.000	0.000
30	3	35.000	35.000	0.000
30	4	30.000	40.000	-10.000
30	5	35.000	35.000	0.000
50	11	40.000	25.000	15.000
50	12	35.000	30.000	5.000
50	13	30.000	35.000	-5.000
50	14	30.000	25.000	5.000
50	15	35.000	25.000	10.000
100	22	25.000	25.000	0.000
100	23	30.000	35.000	-5.000
100	24	25.000	25.000	0.000
100	25	25.000	35.000	-10.000
100	26	30.000	30.000	0.000
100	27	50.000	50.000	0.000
100	28	35.000	40.000	-5.000
100	29	25.000	25.000	0.000
100	30	25.000	25.000	0.000
100	31	30.000	25.000	5.000
100	32	25.000	30.000	-5.000
100	33	25.000	25.000	0.000
100	34	35.000	220.000	-185.000
100	35	30.000	120.000	-90.000
100	36	20.000	130.000	-110.000
100	37	35.000	125.000	-90.000
100	38	20.000	20.000	0.000
100	39	25.000	20.000	5.000
100	40	25.000	25.000	0.000
100	41	25.000	25.000	0.000
100	42	15.000	20.000	-5.000
100	43	30.000	25.000	5.000
100	44	30.000	25.000	5.000
	Max	50.000	220.000	15.000
	Average	29.242	43.182	-13.939
	Min	15.000	20.000	-185.000
	Std Dev	6.510	42.899	42.182

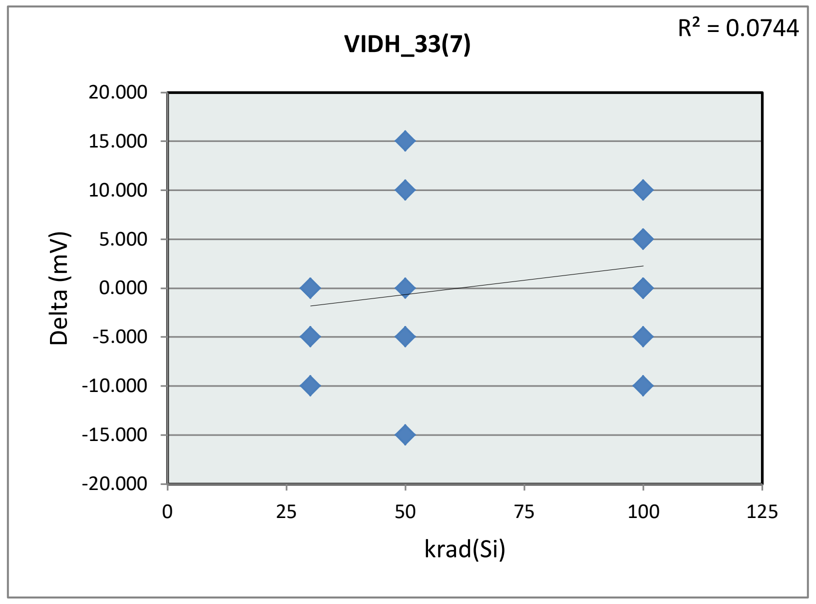


	DVTH_33(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	25.000	25.000	20.000
Average	32.000	28.000	48.913
Max	40.000	35.000	220.000
UL	150.000	150.000	150.000

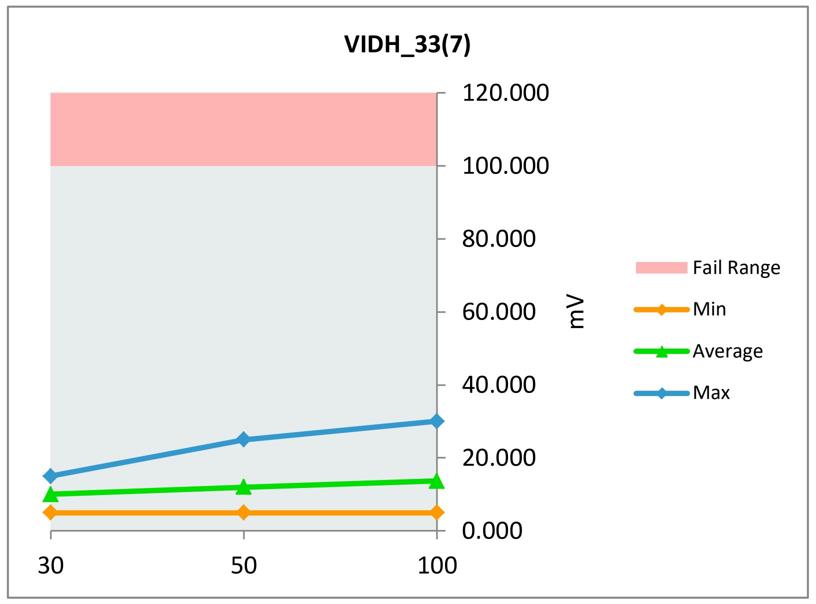


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	10.000	-5.000
30	4	15.000	15.000	0.000
30	5	5.000	15.000	-10.000
50	11	20.000	5.000	15.000
50	12	5.000	20.000	-15.000
50	13	15.000	5.000	10.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	25.000	20.000	5.000
100	24	20.000	15.000	5.000
100	25	30.000	30.000	0.000
100	26	30.000	25.000	5.000
100	27	20.000	15.000	5.000
100	28	5.000	5.000	0.000
100	29	15.000	5.000	10.000
100	30	20.000	20.000	0.000
100	31	5.000	5.000	0.000
100	32	5.000	15.000	-10.000
100	33	25.000	20.000	5.000
100	34	25.000	30.000	-5.000
100	35	5.000	5.000	0.000
100	36	5.000	5.000	0.000
100	37	20.000	15.000	5.000
100	38	20.000	15.000	5.000
100	39	15.000	5.000	10.000
100	40	20.000	20.000	0.000
100	41	5.000	5.000	0.000
100	42	5.000	5.000	0.000
100	43	20.000	15.000	5.000
100	44	20.000	15.000	5.000
	Max	30.000	30.000	15.000
	Average	14.091	12.879	1.212
	Min	5.000	5.000	-15.000
	Std Dev	8.611	8.007	6.128

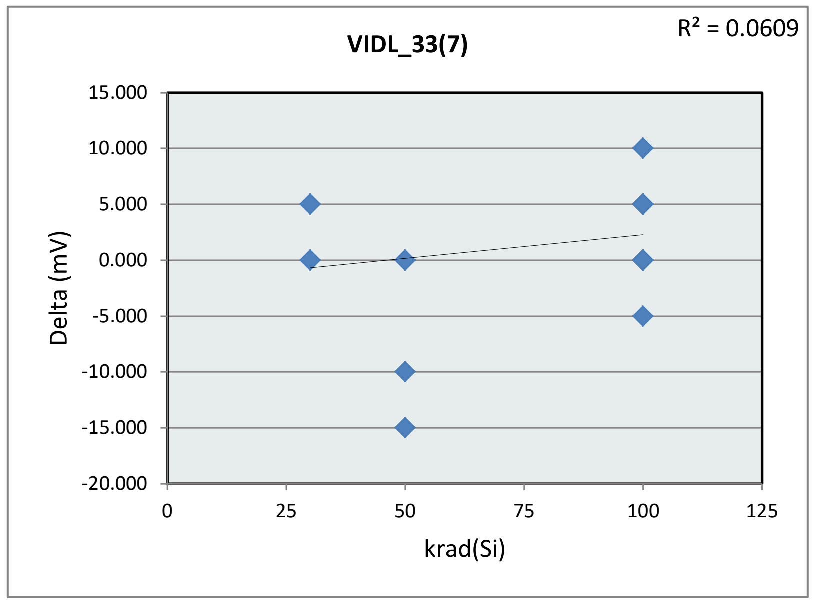


	VIDH_33(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	10.000	12.000	13.696
Max	15.000	25.000	30.000
UL	100.000	100.000	100.000

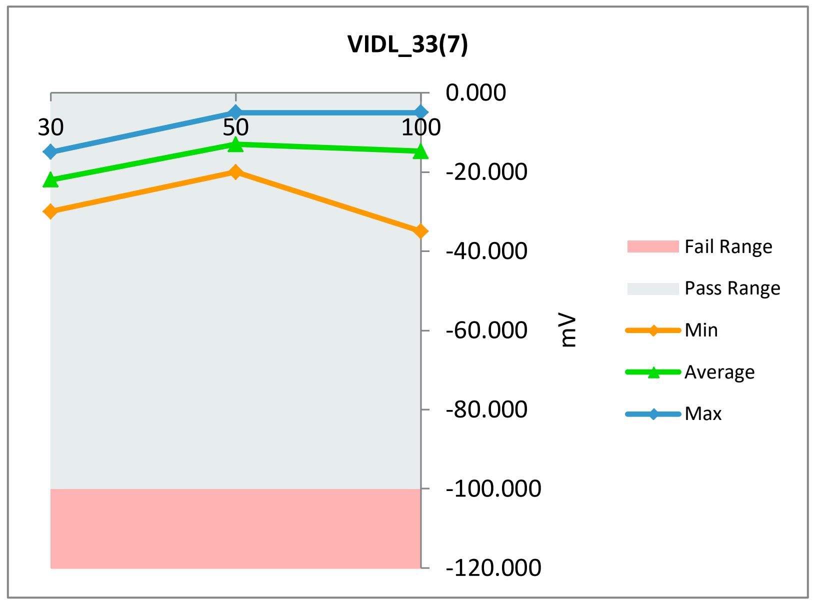


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-25.000	-30.000	5.000
30	2	-10.000	-15.000	5.000
30	3	-25.000	-30.000	5.000
30	4	-15.000	-15.000	0.000
30	5	-20.000	-20.000	0.000
50	11	-15.000	-15.000	0.000
50	12	-20.000	-5.000	-15.000
50	13	-20.000	-20.000	0.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-20.000	-10.000
100	22	-15.000	-15.000	0.000
100	23	-10.000	-5.000	-5.000
100	24	-5.000	-10.000	5.000
100	25	-15.000	-15.000	0.000
100	26	-5.000	-5.000	0.000
100	27	-35.000	-35.000	0.000
100	28	-30.000	-30.000	0.000
100	29	-5.000	-15.000	10.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-25.000	5.000
100	32	-10.000	-15.000	5.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-25.000	5.000
100	36	-25.000	-30.000	5.000
100	37	-20.000	-25.000	5.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	40	-5.000	-15.000	10.000
100	41	-10.000	-10.000	0.000
100	42	-15.000	-20.000	5.000
100	43	-5.000	-10.000	5.000
100	44	-5.000	-10.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-14.091	-15.606	1.515
	Min	-35.000	-35.000	-15.000
	Std Dev	8.966	9.165	4.919



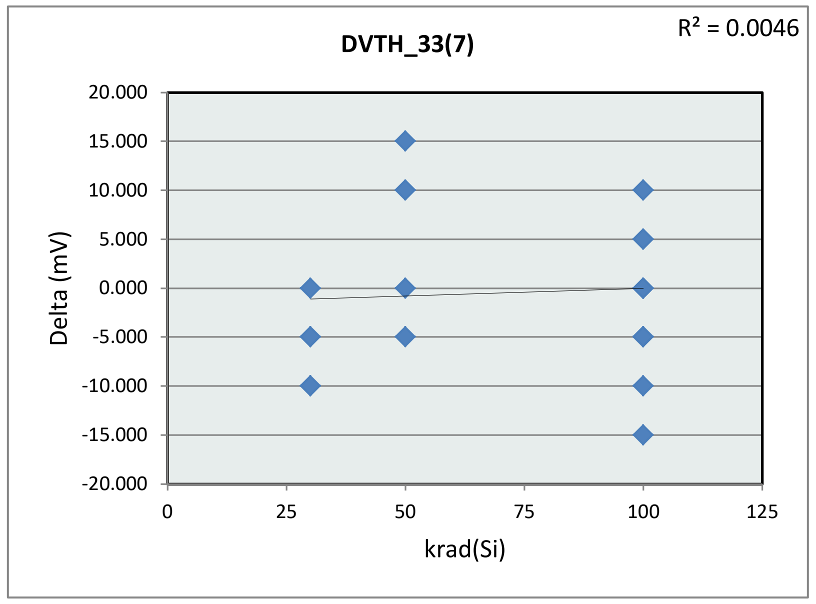
	VIDL_33(7)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-20.000	-35.000
Average	-22.000	-13.000	-14.783
Max	-15.000	-5.000	-5.000
UL			



HDR TID Report T0 data
SN55LVCP22A-SP

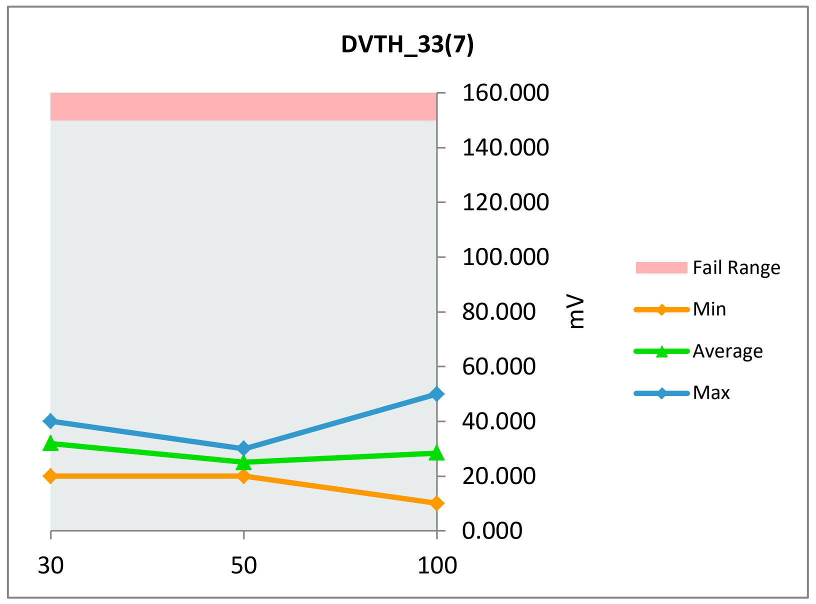
	DVTH_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	30.000	35.000	-5.000
30	2	15.000	20.000	-5.000
30	3	30.000	40.000	-10.000
30	4	30.000	30.000	0.000
30	5	25.000	35.000	-10.000
50	11	35.000	20.000	15.000
50	12	25.000	25.000	0.000
50	13	35.000	25.000	10.000
50	14	25.000	30.000	-5.000
50	15	35.000	25.000	10.000
100	22	20.000	20.000	0.000
100	23	35.000	25.000	10.000
100	24	25.000	25.000	0.000
100	25	45.000	45.000	0.000
100	26	35.000	30.000	5.000
100	27	55.000	50.000	5.000
100	28	35.000	35.000	0.000
100	29	20.000	20.000	0.000
100	30	25.000	25.000	0.000
100	31	25.000	30.000	-5.000
100	32	15.000	30.000	-15.000
100	33	30.000	25.000	5.000
100	34	30.000	35.000	-5.000
100	35	25.000	30.000	-5.000
100	36	30.000	35.000	-5.000
100	37	40.000	40.000	0.000
100	38	25.000	20.000	5.000
100	39	20.000	10.000	10.000
100	40	25.000	35.000	-10.000
100	41	15.000	15.000	0.000
100	42	20.000	25.000	-5.000
100	43	25.000	25.000	0.000
100	44	25.000	25.000	0.000
	Max	55.000	50.000	15.000
	Average	28.182	28.485	-0.303
	Min	15.000	10.000	-15.000
	Std Dev	8.553	8.430	6.724



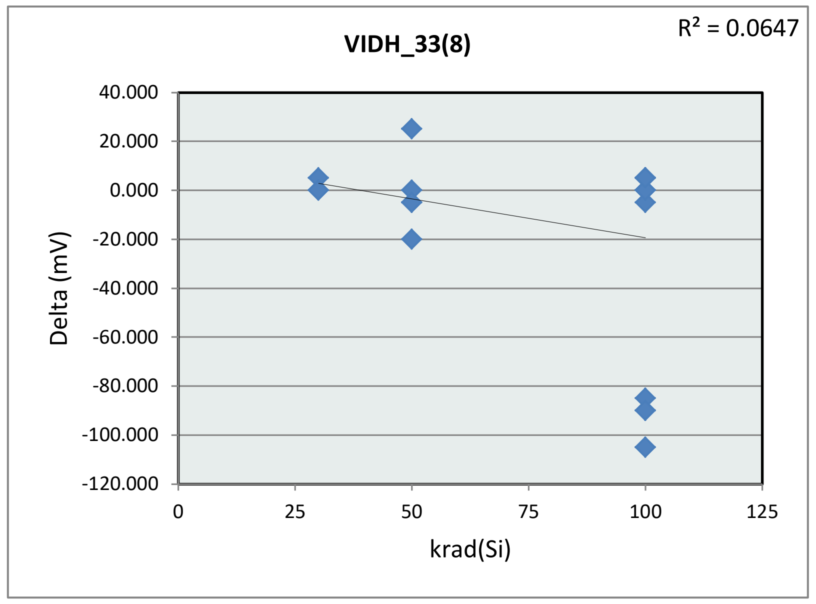
	DVTH_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	mV
Min Limit		mV

krad(Si)	30	50	100
LL			
Min	20.000	20.000	10.000
Average	32.000	25.000	28.478
Max	40.000	30.000	50.000
UL	150.000	150.000	150.000

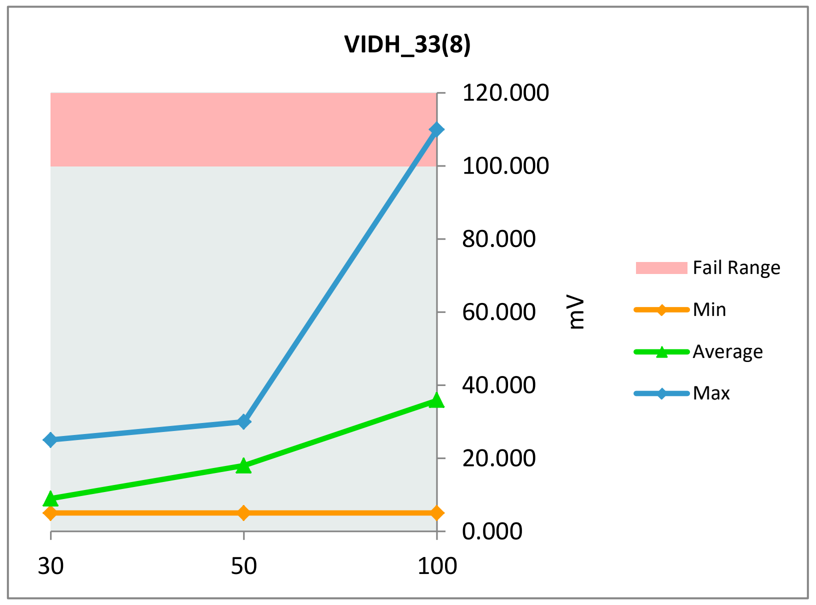


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_33(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	10.000	5.000	5.000
30	2	25.000	25.000	0.000
30	3	5.000	5.000	0.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	25.000	30.000	-5.000
50	13	5.000	25.000	-20.000
50	14	20.000	20.000	0.000
50	15	5.000	10.000	-5.000
100	22	15.000	20.000	-5.000
100	23	20.000	20.000	0.000
100	24	15.000	15.000	0.000
100	25	5.000	110.000	-105.000
100	26	15.000	15.000	0.000
100	27	25.000	25.000	0.000
100	28	15.000	15.000	0.000
100	29	15.000	15.000	0.000
100	30	20.000	15.000	5.000
100	31	15.000	15.000	0.000
100	32	20.000	20.000	0.000
100	33	20.000	20.000	0.000
100	34	20.000	110.000	-90.000
100	35	25.000	110.000	-85.000
100	36	5.000	110.000	-105.000
100	37	20.000	110.000	-90.000
100	38	10.000	5.000	5.000
100	39	15.000	15.000	0.000
100	40	10.000	5.000	5.000
100	41	15.000	10.000	5.000
100	42	5.000	5.000	0.000
100	43	25.000	20.000	5.000
100	44	25.000	20.000	5.000
	Max	30.000	110.000	25.000
	Average	15.455	29.091	-13.636
	Min	5.000	5.000	-105.000
	Std Dev	7.641	35.410	35.625

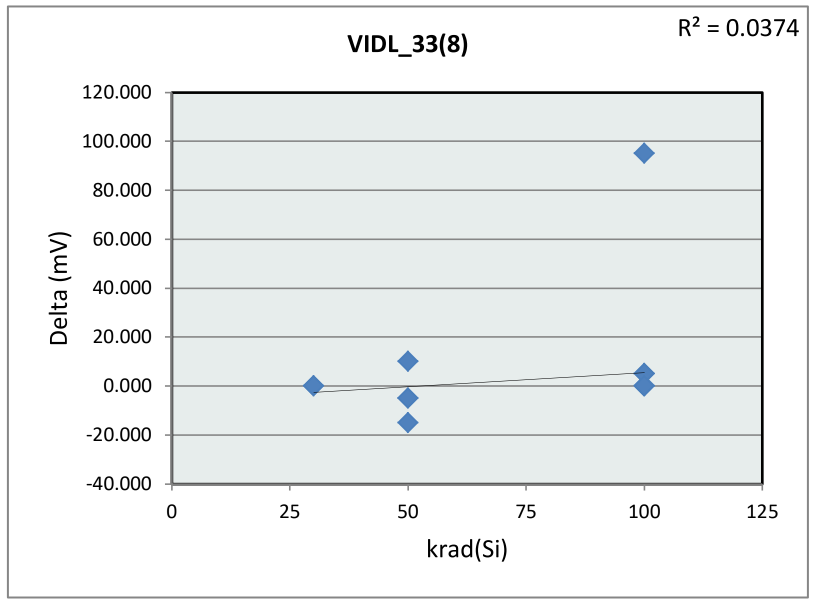


	VIDH_33(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	9.000	18.000	35.870
Max	25.000	30.000	110.000
UL	100.000	100.000	100.000

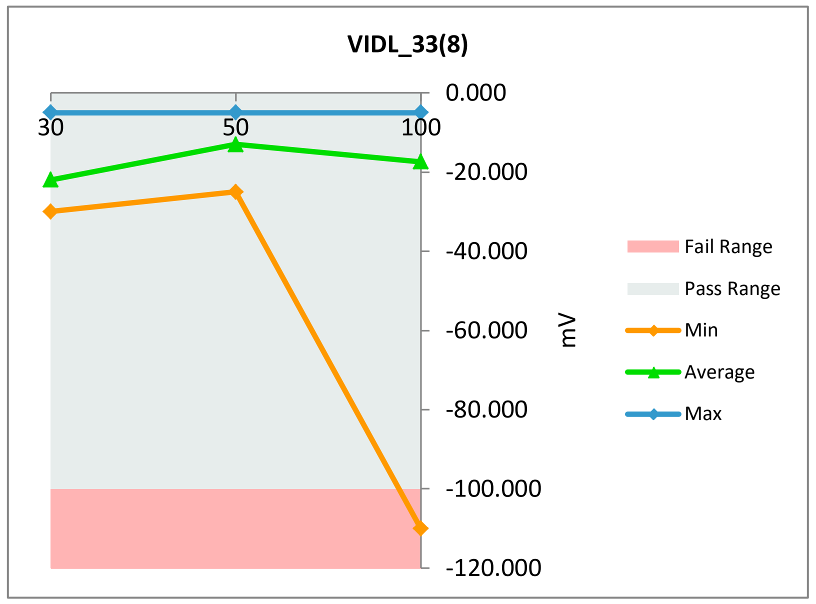


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	-20.000	-20.000	0.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-25.000	-10.000	-15.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-25.000	-5.000
100	22	-10.000	-10.000	0.000
100	23	-15.000	-15.000	0.000
100	24	-10.000	-10.000	0.000
100	25	-25.000	-25.000	0.000
100	26	-10.000	-15.000	5.000
100	27	-25.000	-25.000	0.000
100	28	-20.000	-20.000	0.000
100	29	-5.000	-10.000	5.000
100	30	-5.000	-10.000	5.000
100	31	-10.000	-15.000	5.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-110.000	95.000
100	35	-10.000	-10.000	0.000
100	36	-20.000	-25.000	5.000
100	37	-15.000	-15.000	0.000
100	38	-15.000	-15.000	0.000
100	39	-5.000	-5.000	0.000
100	40	-15.000	-20.000	5.000
100	41	-5.000	-5.000	0.000
100	42	-15.000	-20.000	5.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	95.000
	Average	-14.091	-17.424	3.333
	Min	-30.000	-110.000	-15.000
	Std Dev	8.334	18.503	16.987



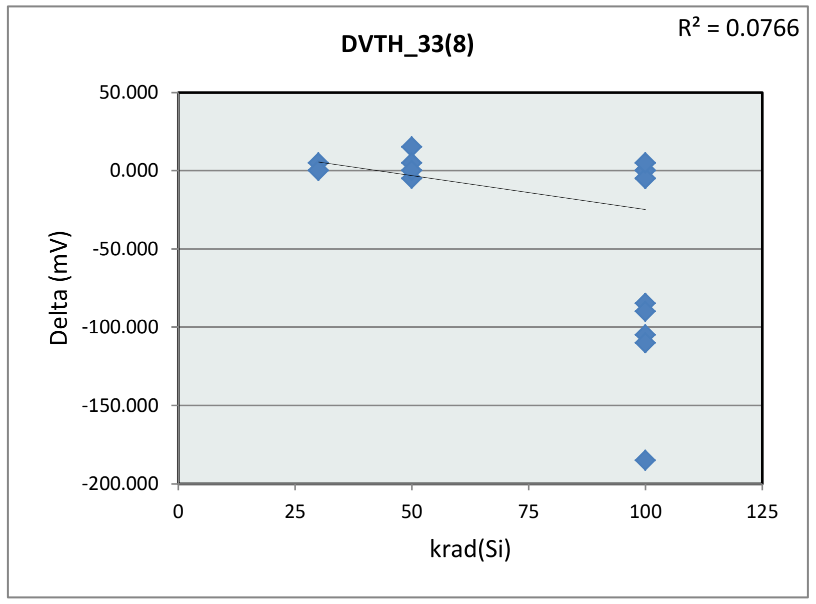
	VIDL_33(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-25.000	-110.000
Average	-22.000	-13.000	-17.391
Max	-5.000	-5.000	-5.000
UL			



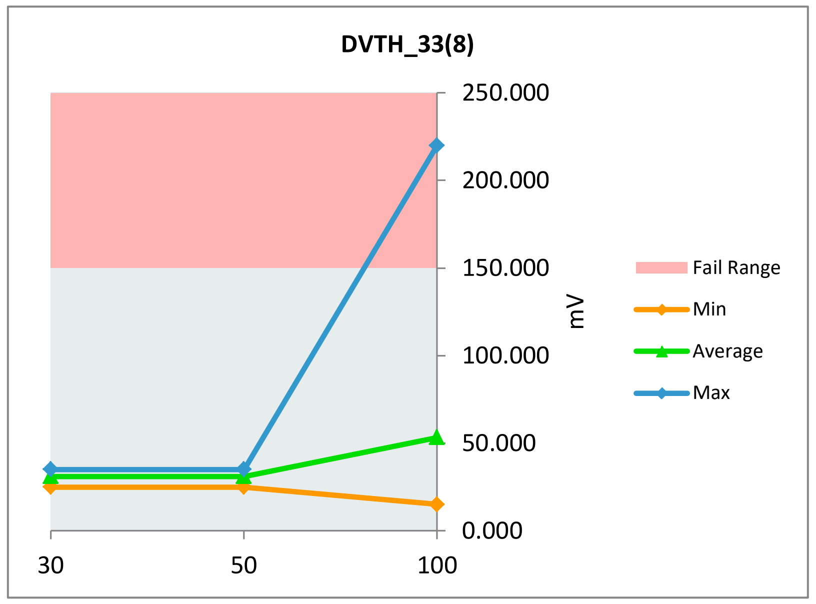
HDR TID Report T0 data
SN55LVCP22A-SP

	DVTH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	30.000	25.000	5.000
30	2	30.000	30.000	0.000
30	3	35.000	35.000	0.000
30	4	30.000	30.000	0.000
30	5	35.000	35.000	0.000
50	11	40.000	25.000	15.000
50	12	35.000	35.000	0.000
50	13	30.000	35.000	-5.000
50	14	30.000	25.000	5.000
50	15	35.000	35.000	0.000
100	22	25.000	30.000	-5.000
100	23	35.000	35.000	0.000
100	24	25.000	25.000	0.000
100	25	30.000	135.000	-105.000
100	26	25.000	30.000	-5.000
100	27	50.000	50.000	0.000
100	28	35.000	35.000	0.000
100	29	20.000	25.000	-5.000
100	30	25.000	25.000	0.000
100	31	25.000	30.000	-5.000
100	32	25.000	25.000	0.000
100	33	25.000	25.000	0.000
100	34	35.000	220.000	-185.000
100	35	35.000	120.000	-85.000
100	36	25.000	135.000	-110.000
100	37	35.000	125.000	-90.000
100	38	25.000	20.000	5.000
100	39	20.000	20.000	0.000
100	40	25.000	25.000	0.000
100	41	20.000	15.000	5.000
100	42	20.000	25.000	-5.000
100	43	30.000	25.000	5.000
100	44	30.000	25.000	5.000
	Max	50.000	220.000	15.000
	Average	29.545	46.515	-16.970
	Min	20.000	15.000	-185.000
	Std Dev	6.539	45.953	44.615

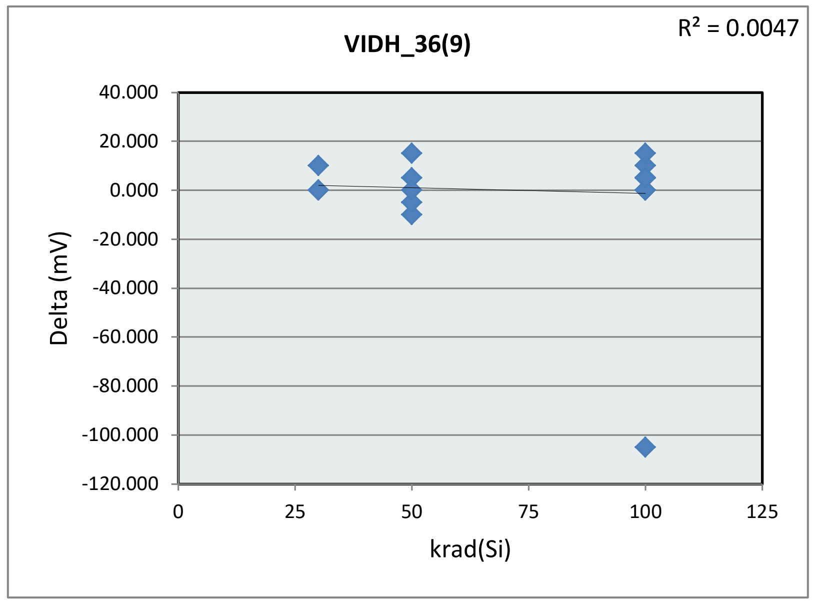


	DVTH_33(8)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	25.000	25.000	15.000
Average	31.000	31.000	53.261
Max	35.000	35.000	220.000
UL	150.000	150.000	150.000

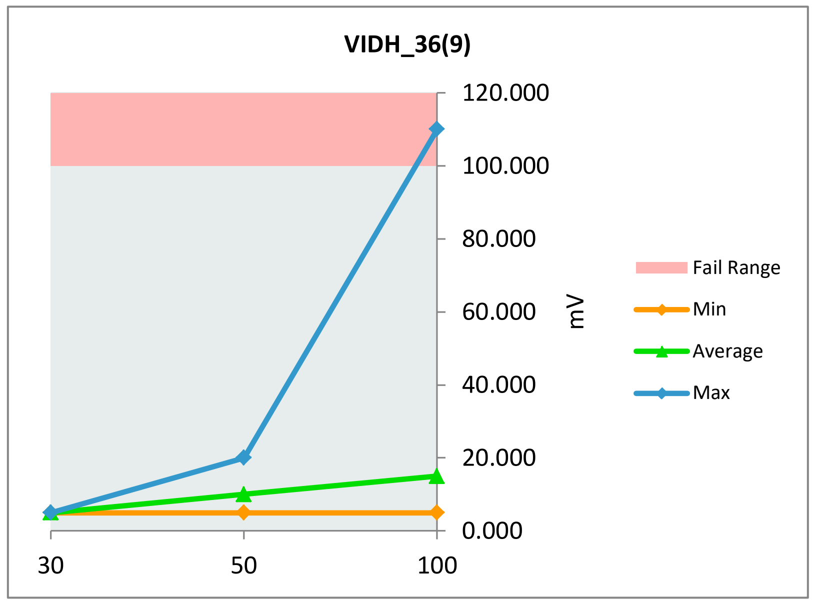


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	5.000	0.000
30	4	15.000	5.000	10.000
30	5	5.000	5.000	0.000
50	11	20.000	5.000	15.000
50	12	5.000	15.000	-10.000
50	13	10.000	5.000	5.000
50	14	15.000	20.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	20.000	20.000	0.000
100	24	5.000	5.000	0.000
100	25	30.000	25.000	5.000
100	26	30.000	25.000	5.000
100	27	15.000	5.000	10.000
100	28	5.000	5.000	0.000
100	29	15.000	5.000	10.000
100	30	5.000	5.000	0.000
100	31	5.000	5.000	0.000
100	32	15.000	10.000	5.000
100	33	20.000	5.000	15.000
100	34	25.000	25.000	0.000
100	35	5.000	5.000	0.000
100	36	5.000	5.000	0.000
100	37	5.000	5.000	0.000
100	38	20.000	15.000	5.000
100	39	5.000	110.000	-105.000
100	40	20.000	15.000	5.000
100	41	15.000	10.000	5.000
100	42	5.000	5.000	0.000
100	43	20.000	15.000	5.000
100	44	20.000	15.000	5.000
	Max	30.000	110.000	15.000
	Average	12.273	12.727	-0.455
	Min	5.000	5.000	-105.000
	Std Dev	8.110	18.754	19.460

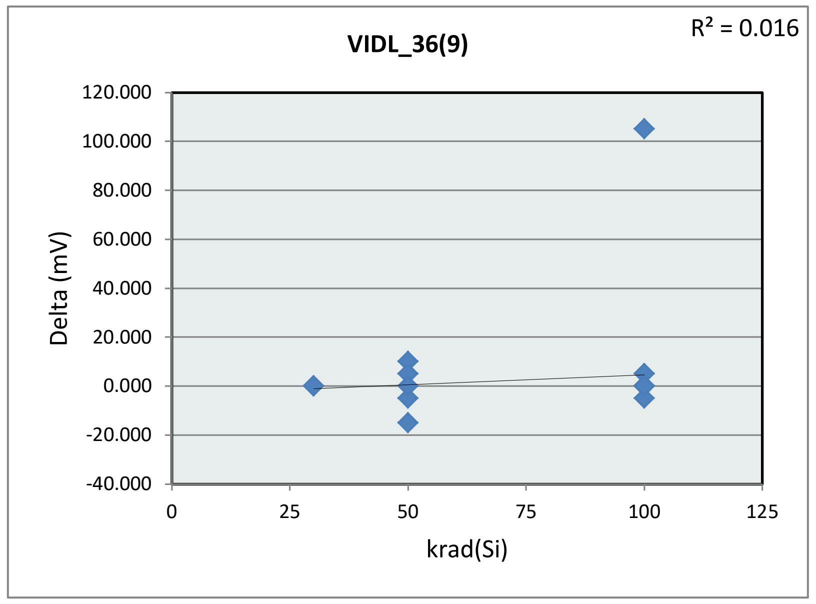


	VIDH_36(9)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	5.000	10.000	15.000
Max	5.000	20.000	110.000
UL	100.000	100.000	100.000

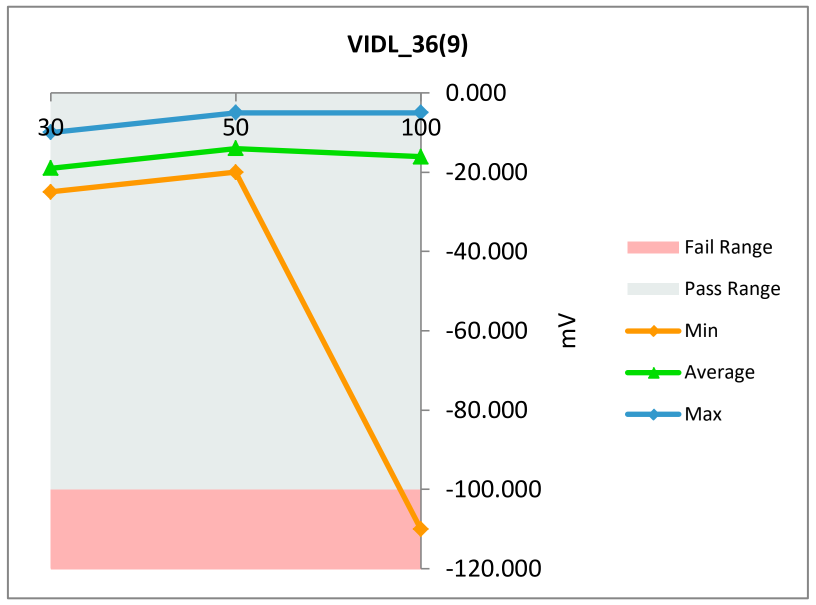


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-25.000	-25.000	0.000
30	2	-10.000	-10.000	0.000
30	3	-25.000	-25.000	0.000
30	4	-15.000	-15.000	0.000
30	5	-20.000	-20.000	0.000
50	11	-5.000	-15.000	10.000
50	12	-20.000	-15.000	-5.000
50	13	-15.000	-20.000	5.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-15.000	-15.000
100	22	-10.000	-10.000	0.000
100	23	-5.000	-5.000	0.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-15.000	0.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-35.000	5.000
100	28	-30.000	-30.000	0.000
100	29	-5.000	-10.000	5.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-20.000	0.000
100	32	-10.000	-5.000	-5.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-20.000	0.000
100	36	-25.000	-25.000	0.000
100	37	-20.000	-20.000	0.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-110.000	105.000
100	40	-5.000	-5.000	0.000
100	41	-5.000	-5.000	0.000
100	42	-15.000	-15.000	0.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	105.000
	Average	-13.030	-16.212	3.182
	Min	-30.000	-110.000	-15.000
	Std Dev	8.921	18.876	18.659

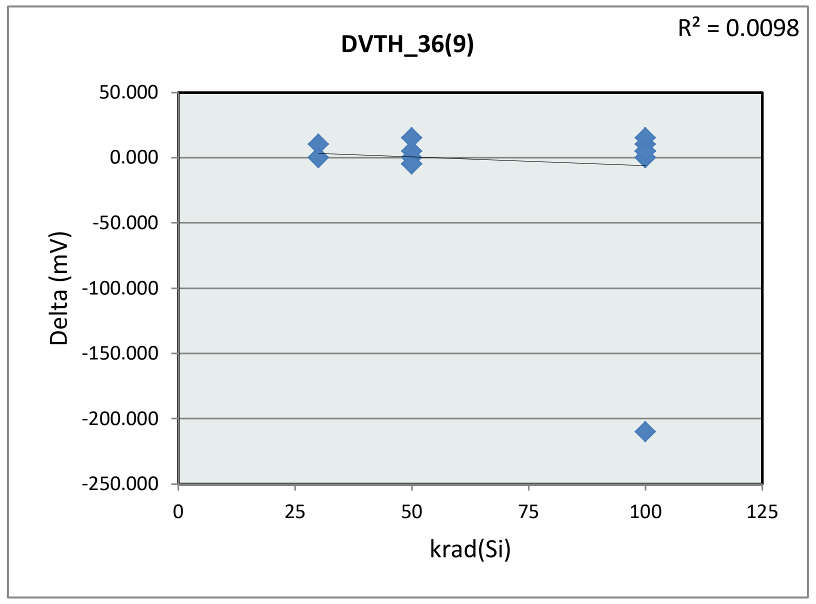


	VIDL_36(9)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-25.000	-20.000	-110.000
Average	-19.000	-14.000	-16.087
Max	-10.000	-5.000	-5.000
UL			

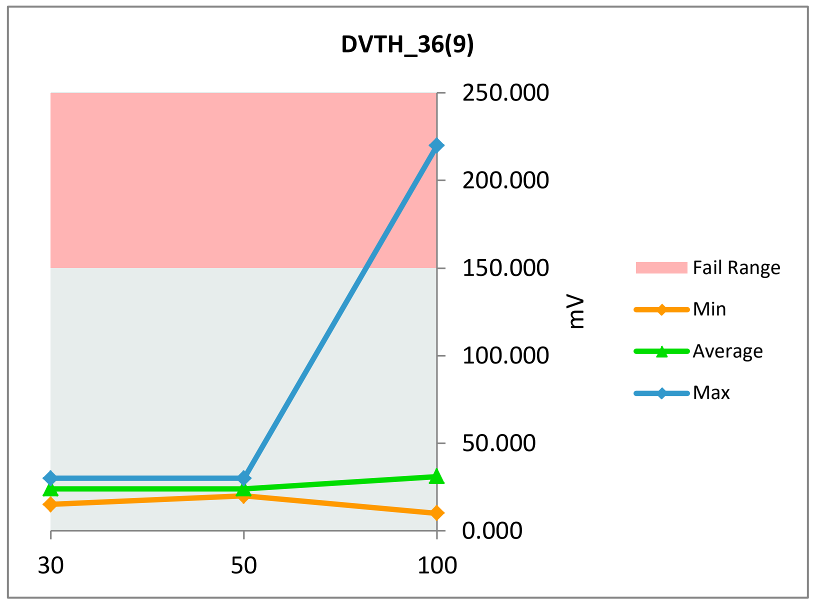


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	30.000	30.000	0.000
30	2	15.000	15.000	0.000
30	3	30.000	30.000	0.000
30	4	30.000	20.000	10.000
30	5	25.000	25.000	0.000
50	11	25.000	20.000	5.000
50	12	25.000	30.000	-5.000
50	13	25.000	25.000	0.000
50	14	20.000	25.000	-5.000
50	15	35.000	20.000	15.000
100	22	15.000	15.000	0.000
100	23	25.000	25.000	0.000
100	24	10.000	10.000	0.000
100	25	45.000	40.000	5.000
100	26	35.000	30.000	5.000
100	27	45.000	40.000	5.000
100	28	35.000	35.000	0.000
100	29	20.000	15.000	5.000
100	30	10.000	10.000	0.000
100	31	25.000	25.000	0.000
100	32	25.000	15.000	10.000
100	33	25.000	10.000	15.000
100	34	30.000	30.000	0.000
100	35	25.000	25.000	0.000
100	36	30.000	30.000	0.000
100	37	25.000	25.000	0.000
100	38	25.000	20.000	5.000
100	39	10.000	220.000	-210.000
100	40	25.000	20.000	5.000
100	41	20.000	15.000	5.000
100	42	20.000	20.000	0.000
100	43	25.000	20.000	5.000
100	44	25.000	20.000	5.000
	Max	45.000	220.000	15.000
	Average	25.303	28.939	-3.636
	Min	10.000	10.000	-210.000
	Std Dev	8.286	35.173	37.339

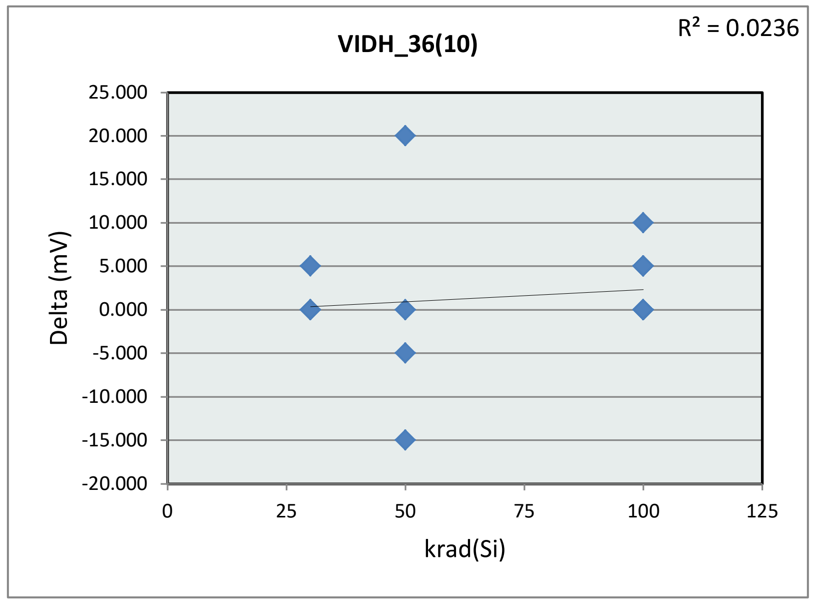


	DVTH_36(9)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	15.000	20.000	10.000
Average	24.000	24.000	31.087
Max	30.000	30.000	220.000
UL	150.000	150.000	150.000

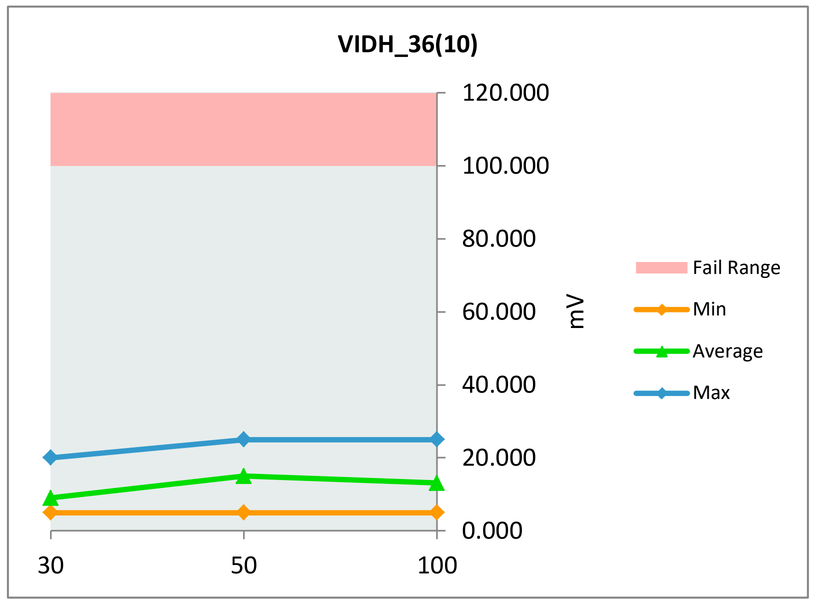


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_36(10)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	20.000	20.000	0.000
30	3	5.000	5.000	0.000
30	4	15.000	10.000	5.000
30	5	5.000	5.000	0.000
50	11	25.000	5.000	20.000
50	12	25.000	25.000	0.000
50	13	5.000	20.000	-15.000
50	14	15.000	20.000	-5.000
50	15	5.000	5.000	0.000
100	22	15.000	15.000	0.000
100	23	20.000	20.000	0.000
100	24	15.000	15.000	0.000
100	25	5.000	5.000	0.000
100	26	15.000	15.000	0.000
100	27	25.000	25.000	0.000
100	28	15.000	5.000	10.000
100	29	15.000	15.000	0.000
100	30	15.000	10.000	5.000
100	31	15.000	15.000	0.000
100	32	15.000	15.000	0.000
100	33	20.000	15.000	5.000
100	34	20.000	15.000	5.000
100	35	20.000	15.000	5.000
100	36	5.000	5.000	0.000
100	37	20.000	15.000	5.000
100	38	5.000	5.000	0.000
100	39	15.000	15.000	0.000
100	40	10.000	5.000	5.000
100	41	15.000	10.000	5.000
100	42	5.000	5.000	0.000
100	43	25.000	20.000	5.000
100	44	25.000	20.000	5.000
	Max	25.000	25.000	20.000
	Average	14.545	12.727	1.818
	Min	5.000	5.000	-15.000
	Std Dev	7.000	6.506	5.276

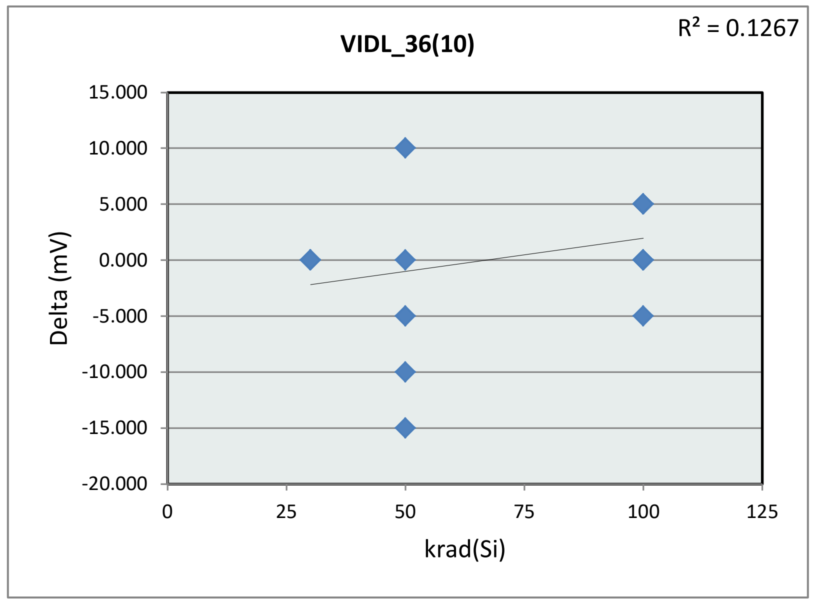


	VIDH_36(10)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	9.000	15.000	13.043
Max	20.000	25.000	25.000
UL	100.000	100.000	100.000

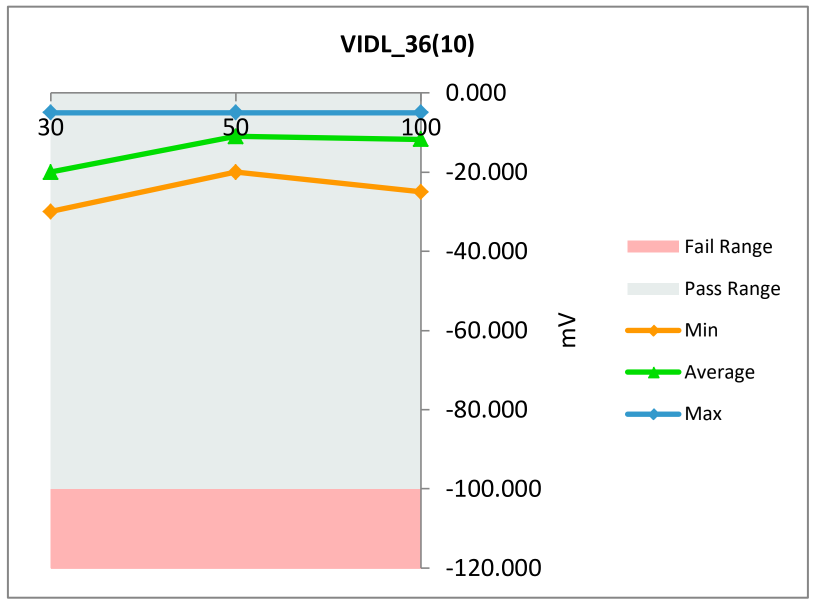


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-15.000	-15.000	0.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-25.000	-25.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-20.000	-5.000	-15.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-20.000	-10.000
100	22	-5.000	-10.000	5.000
100	23	-10.000	-15.000	5.000
100	24	-5.000	-10.000	5.000
100	25	-20.000	-25.000	5.000
100	26	-10.000	-10.000	0.000
100	27	-20.000	-25.000	5.000
100	28	-20.000	-25.000	5.000
100	29	-5.000	-5.000	0.000
100	30	-10.000	-5.000	-5.000
100	31	-5.000	-5.000	0.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-10.000	-10.000	0.000
100	35	-10.000	-10.000	0.000
100	36	-15.000	-20.000	5.000
100	37	-10.000	-15.000	5.000
100	38	-10.000	-15.000	5.000
100	39	-5.000	-5.000	0.000
100	40	-15.000	-20.000	5.000
100	41	-5.000	-5.000	0.000
100	42	-10.000	-15.000	5.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-11.970	-12.879	0.909
	Min	-30.000	-30.000	-15.000
	Std Dev	7.699	8.104	4.752

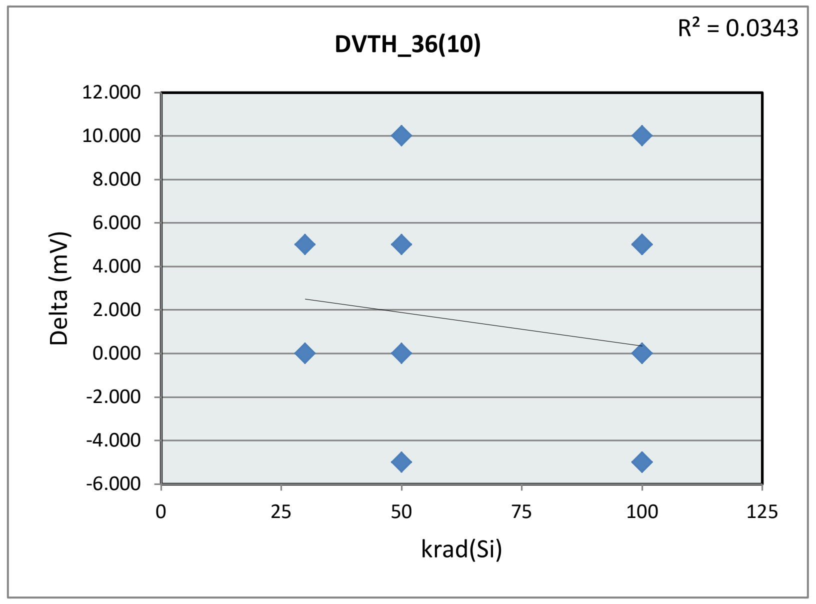


	VIDL_36(10)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-20.000	-25.000
Average	-20.000	-11.000	-11.739
Max	-5.000	-5.000	-5.000
UL			

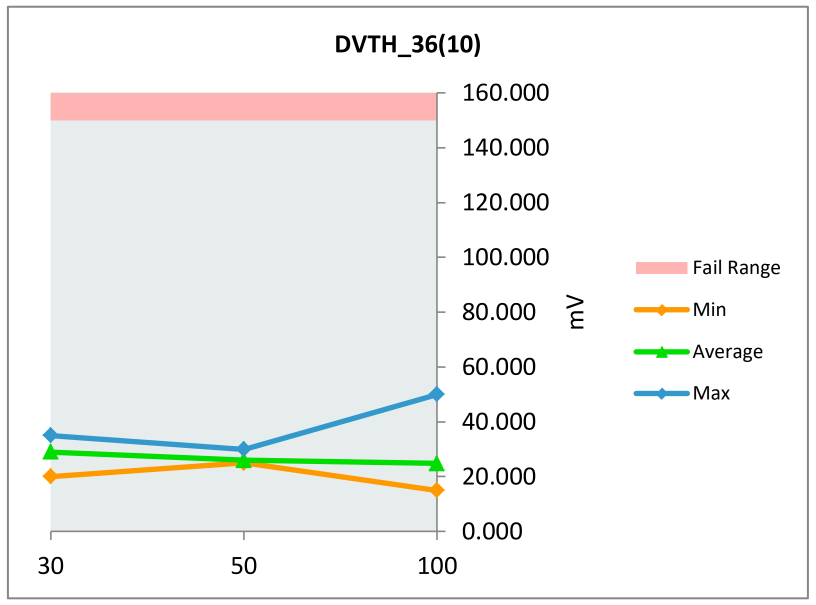


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	20.000	20.000	0.000
30	2	25.000	25.000	0.000
30	3	35.000	35.000	0.000
30	4	40.000	35.000	5.000
30	5	30.000	30.000	0.000
50	11	35.000	25.000	10.000
50	12	35.000	30.000	5.000
50	13	25.000	25.000	0.000
50	14	20.000	25.000	-5.000
50	15	35.000	25.000	10.000
100	22	20.000	25.000	-5.000
100	23	30.000	35.000	-5.000
100	24	20.000	25.000	-5.000
100	25	25.000	30.000	-5.000
100	26	25.000	25.000	0.000
100	27	45.000	50.000	-5.000
100	28	35.000	30.000	5.000
100	29	20.000	20.000	0.000
100	30	25.000	15.000	10.000
100	31	20.000	20.000	0.000
100	32	20.000	20.000	0.000
100	33	25.000	20.000	5.000
100	34	30.000	25.000	5.000
100	35	30.000	25.000	5.000
100	36	20.000	25.000	-5.000
100	37	30.000	30.000	0.000
100	38	15.000	20.000	-5.000
100	39	20.000	20.000	0.000
100	40	25.000	25.000	0.000
100	41	20.000	15.000	5.000
100	42	15.000	20.000	-5.000
100	43	30.000	25.000	5.000
100	44	30.000	25.000	5.000
	Max	45.000	50.000	10.000
	Average	26.515	25.606	0.909
	Min	15.000	15.000	-5.000
	Std Dev	7.233	6.703	4.752

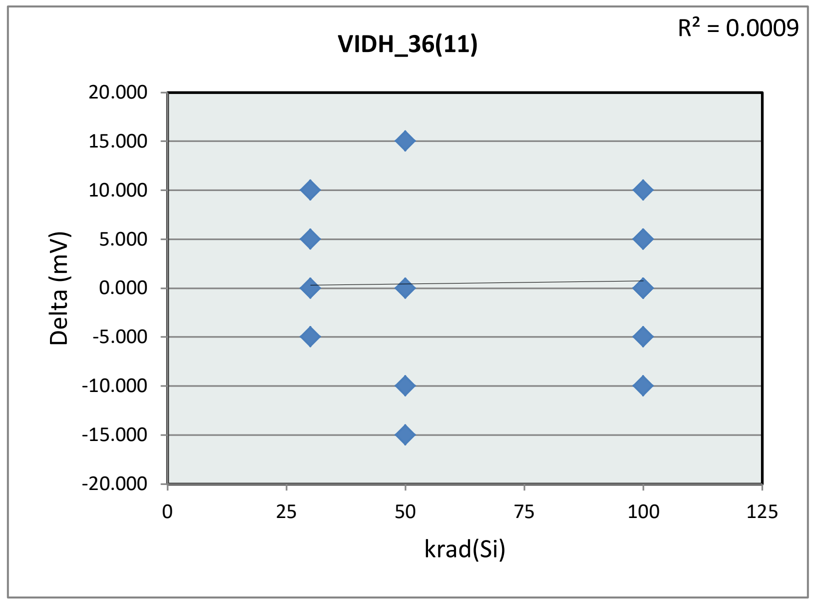


	DVTH_36(10)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	20.000	25.000	15.000
Average	29.000	26.000	24.783
Max	35.000	30.000	50.000
UL	150.000	150.000	150.000

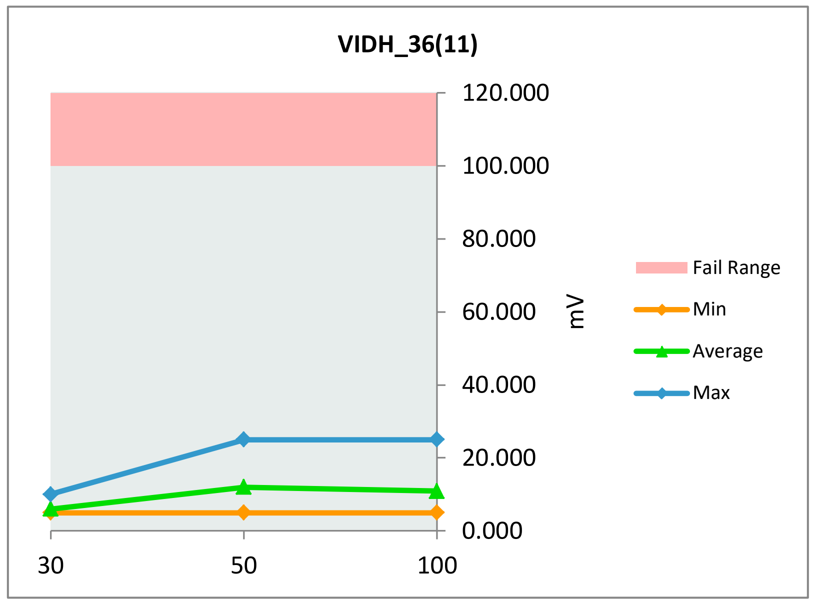


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	10.000	-5.000
30	4	15.000	5.000	10.000
30	5	10.000	5.000	5.000
50	11	20.000	5.000	15.000
50	12	5.000	20.000	-15.000
50	13	5.000	5.000	0.000
50	14	15.000	25.000	-10.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	20.000	20.000	0.000
100	24	5.000	5.000	0.000
100	25	30.000	25.000	5.000
100	26	30.000	25.000	5.000
100	27	15.000	5.000	10.000
100	28	5.000	5.000	0.000
100	29	5.000	5.000	0.000
100	30	20.000	15.000	5.000
100	31	5.000	5.000	0.000
100	32	5.000	5.000	0.000
100	33	20.000	15.000	5.000
100	34	25.000	25.000	0.000
100	35	5.000	10.000	-5.000
100	36	5.000	5.000	0.000
100	37	5.000	15.000	-10.000
100	38	20.000	15.000	5.000
100	39	5.000	10.000	-5.000
100	40	20.000	15.000	5.000
100	41	5.000	5.000	0.000
100	42	5.000	5.000	0.000
100	43	5.000	5.000	0.000
100	44	5.000	5.000	0.000
	Max	30.000	25.000	15.000
	Average	10.909	10.303	0.606
	Min	5.000	5.000	-15.000
	Std Dev	8.240	7.282	5.831

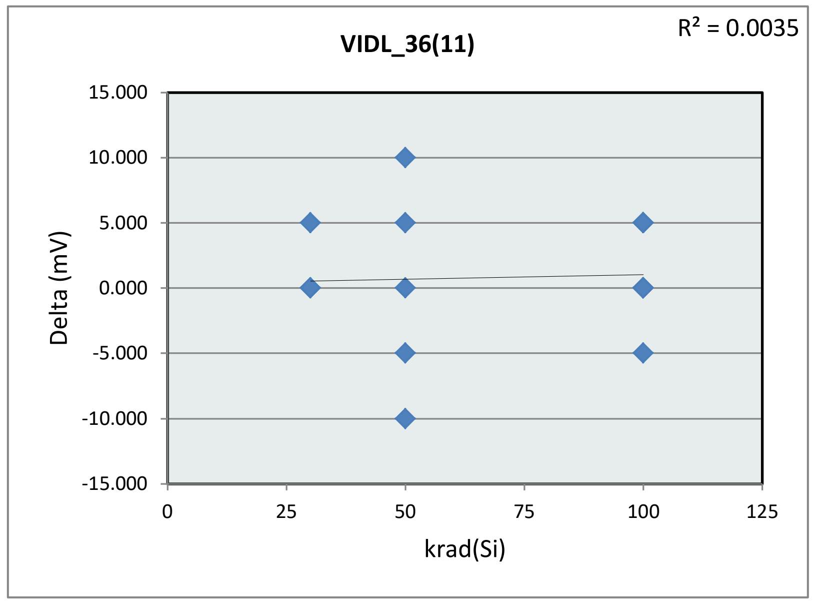


	VIDH_36(11)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	6.000	12.000	10.870
Max	10.000	25.000	25.000
UL	100.000	100.000	100.000

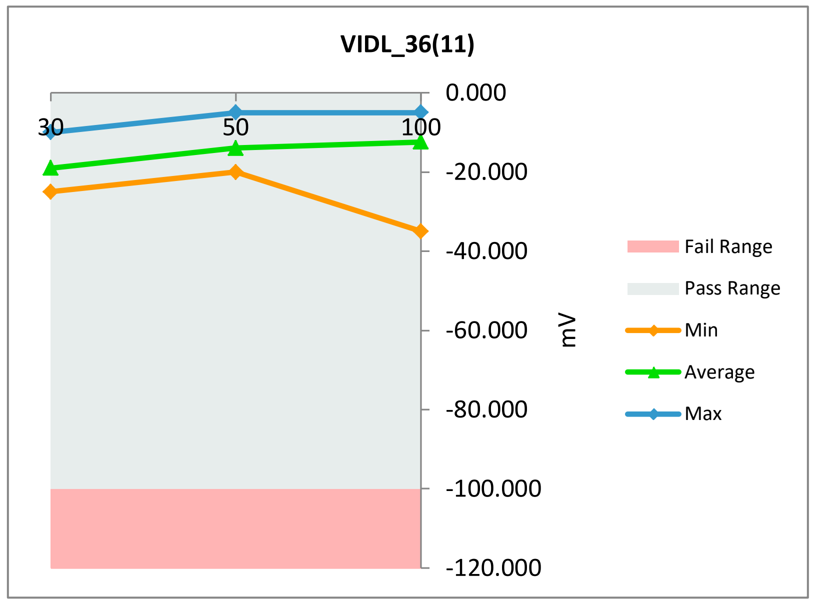


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	-25.000	-25.000	0.000
30	2	-10.000	-10.000	0.000
30	3	-25.000	-25.000	0.000
30	4	-15.000	-15.000	0.000
30	5	-15.000	-20.000	5.000
50	11	-5.000	-15.000	10.000
50	12	-20.000	-15.000	-5.000
50	13	-15.000	-20.000	5.000
50	14	-5.000	-5.000	0.000
50	15	-25.000	-15.000	-10.000
100	22	-10.000	-15.000	5.000
100	23	-5.000	-5.000	0.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-20.000	5.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-35.000	5.000
100	28	-30.000	-30.000	0.000
100	29	-5.000	-10.000	5.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-20.000	0.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-20.000	0.000
100	36	-25.000	-30.000	5.000
100	37	-20.000	-20.000	0.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	40	-5.000	-10.000	5.000
100	41	-10.000	-5.000	-5.000
100	42	-15.000	-15.000	0.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-12.727	-13.636	0.909
	Min	-30.000	-35.000	-10.000
	Std Dev	8.578	8.863	3.635



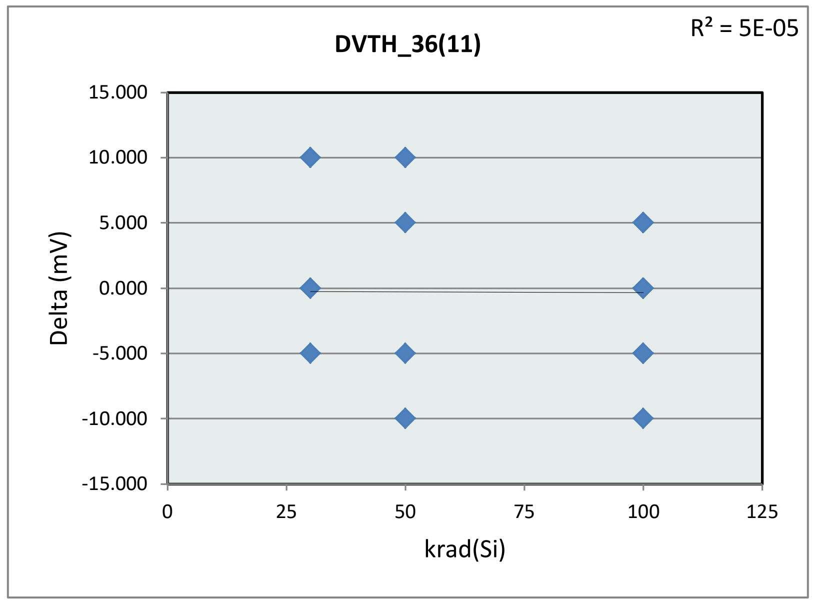
	VIDL_36(11)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-25.000	-20.000	-35.000
Average	-19.000	-14.000	-12.391
Max	-10.000	-5.000	-5.000
UL			



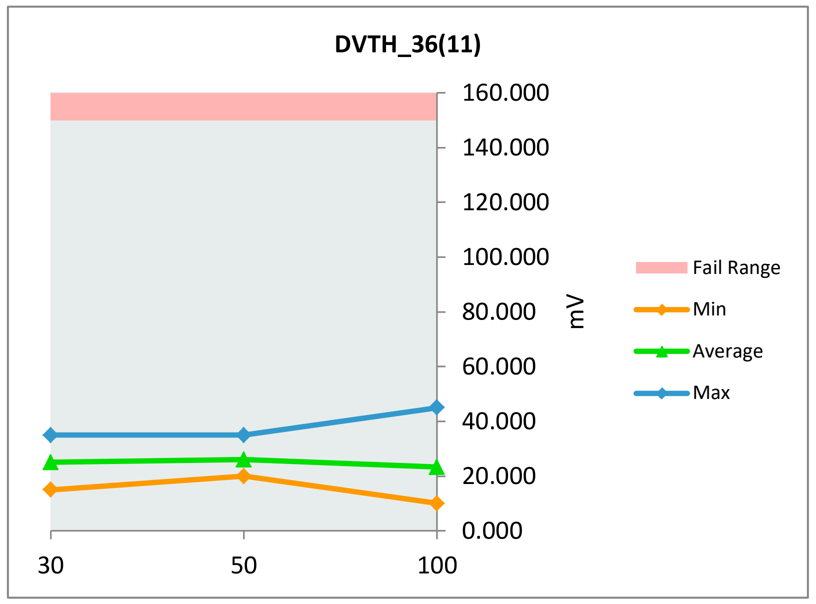
HDR TID Report T0 data
SN55LVCP22A-SP

	DVTH_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	30.000	30.000	0.000
30	2	15.000	15.000	0.000
30	3	30.000	35.000	-5.000
30	4	30.000	20.000	10.000
30	5	25.000	25.000	0.000
50	11	25.000	20.000	5.000
50	12	25.000	35.000	-10.000
50	13	20.000	25.000	-5.000
50	14	20.000	30.000	-10.000
50	15	30.000	20.000	10.000
100	22	15.000	20.000	-5.000
100	23	25.000	25.000	0.000
100	24	10.000	10.000	0.000
100	25	45.000	45.000	0.000
100	26	35.000	30.000	5.000
100	27	45.000	40.000	5.000
100	28	35.000	35.000	0.000
100	29	10.000	15.000	-5.000
100	30	25.000	20.000	5.000
100	31	25.000	25.000	0.000
100	32	10.000	10.000	0.000
100	33	25.000	20.000	5.000
100	34	30.000	30.000	0.000
100	35	25.000	30.000	-5.000
100	36	30.000	35.000	-5.000
100	37	25.000	35.000	-10.000
100	38	25.000	20.000	5.000
100	39	10.000	15.000	-5.000
100	40	25.000	25.000	0.000
100	41	15.000	10.000	5.000
100	42	20.000	20.000	0.000
100	43	10.000	10.000	0.000
100	44	10.000	10.000	0.000
	Max	45.000	45.000	10.000
	Average	23.636	23.939	-0.303
	Min	10.000	10.000	-10.000
	Std Dev	9.377	9.417	5.145

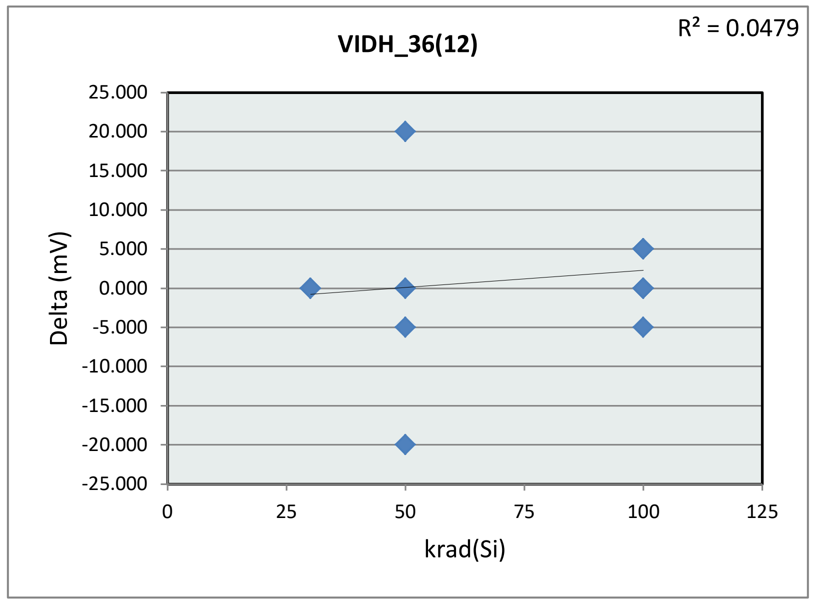


	DVTH_36(11)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	15.000	20.000	10.000
Average	25.000	26.000	23.261
Max	35.000	35.000	45.000
UL	150.000	150.000	150.000

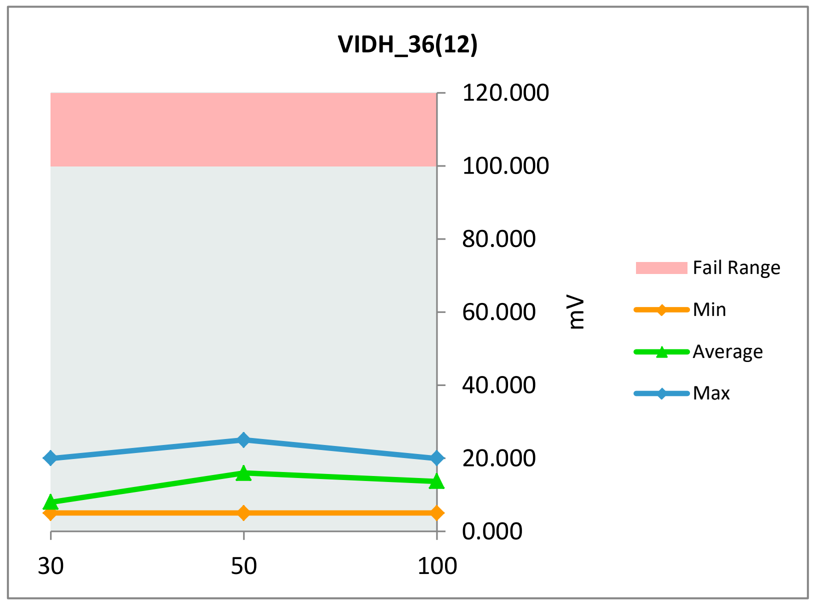


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	5.000	5.000	0.000
30	2	20.000	20.000	0.000
30	3	5.000	5.000	0.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	25.000	5.000	20.000
50	12	25.000	25.000	0.000
50	13	5.000	25.000	-20.000
50	14	15.000	20.000	-5.000
50	15	5.000	5.000	0.000
100	22	10.000	10.000	0.000
100	23	20.000	15.000	5.000
100	24	10.000	15.000	-5.000
100	25	20.000	20.000	0.000
100	26	15.000	15.000	0.000
100	27	20.000	20.000	0.000
100	28	15.000	10.000	5.000
100	29	15.000	10.000	5.000
100	30	15.000	10.000	5.000
100	31	15.000	10.000	5.000
100	32	20.000	15.000	5.000
100	33	20.000	20.000	0.000
100	34	20.000	20.000	0.000
100	35	20.000	20.000	0.000
100	36	5.000	5.000	0.000
100	37	20.000	15.000	5.000
100	38	10.000	5.000	5.000
100	39	20.000	15.000	5.000
100	40	10.000	5.000	5.000
100	41	15.000	15.000	0.000
100	42	5.000	5.000	0.000
100	43	25.000	20.000	5.000
100	44	25.000	20.000	5.000
	Max	25.000	25.000	20.000
	Average	14.697	13.182	1.515
	Min	5.000	5.000	-20.000
	Std Dev	6.953	6.710	5.794

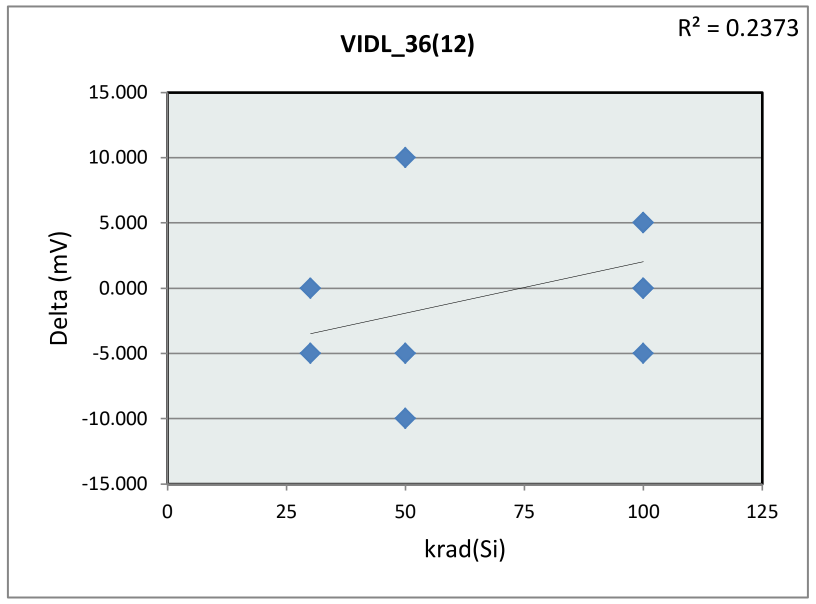


	VIDH_36(12)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	100	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	5.000	5.000	5.000
Average	8.000	16.000	13.696
Max	20.000	25.000	20.000
UL	100.000	100.000	100.000

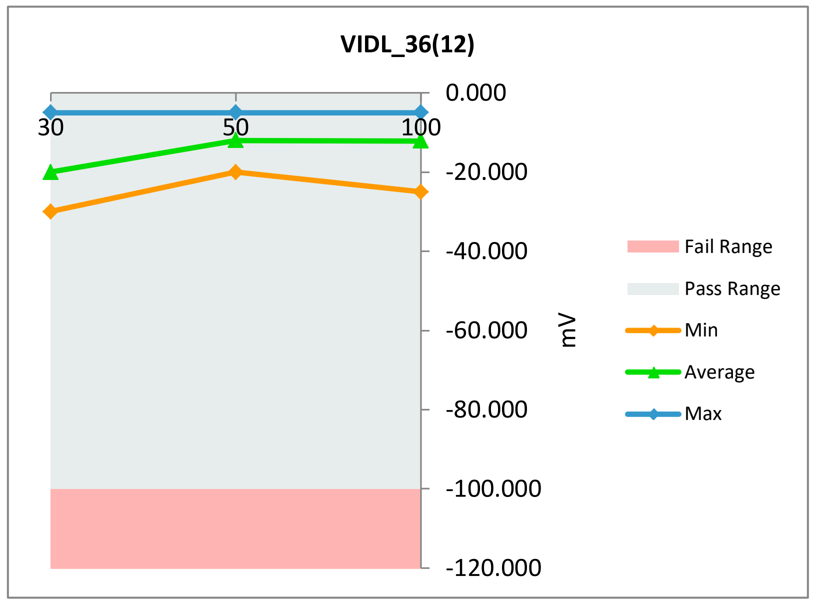


HDR TID Report T0 data
SN55LVCP22A-SP

		VIDL_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-20.000	-15.000	-5.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-25.000	-5.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-20.000	-10.000	-10.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-5.000	-5.000	0.000
100	23	-10.000	-15.000	5.000
100	24	-5.000	-10.000	5.000
100	25	-20.000	-25.000	5.000
100	26	-10.000	-10.000	0.000
100	27	-20.000	-25.000	5.000
100	28	-20.000	-20.000	0.000
100	29	-10.000	-5.000	-5.000
100	30	-5.000	-10.000	5.000
100	31	-10.000	-10.000	0.000
100	32	-5.000	-10.000	5.000
100	33	-5.000	-5.000	0.000
100	34	-10.000	-15.000	5.000
100	35	-10.000	-10.000	0.000
100	36	-15.000	-20.000	5.000
100	37	-10.000	-15.000	5.000
100	38	-10.000	-15.000	5.000
100	39	-5.000	-5.000	0.000
100	40	-15.000	-20.000	5.000
100	41	-5.000	-5.000	0.000
100	42	-15.000	-15.000	0.000
100	43	-5.000	-5.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-12.727	-13.333	0.606
	Min	-30.000	-30.000	-10.000
	Std Dev	7.915	7.569	4.636

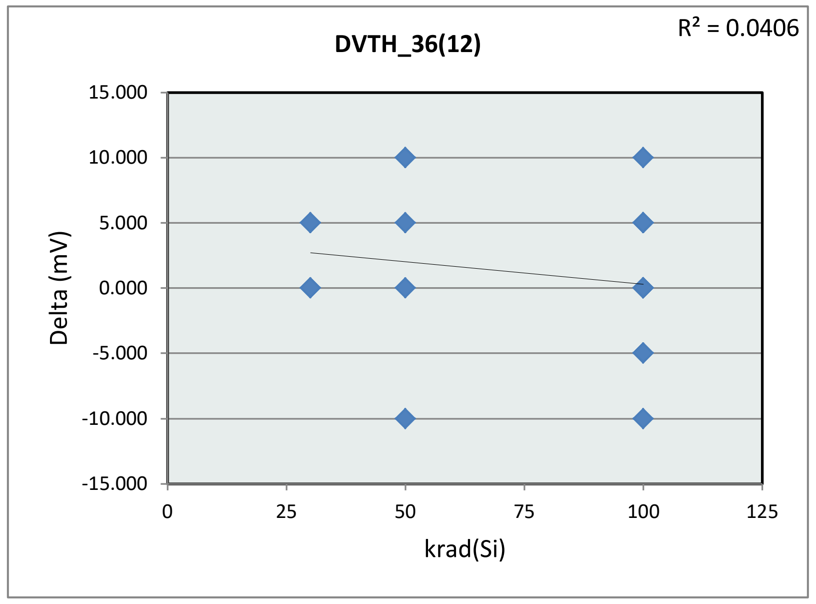


	VIDL_36(12)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit		mV	
Min Limit	-100	mV	
krad(Si)	30	50	100
LL	-100.000	-100.000	-100.000
Min	-30.000	-20.000	-25.000
Average	-20.000	-12.000	-12.174
Max	-5.000	-5.000	-5.000
UL			

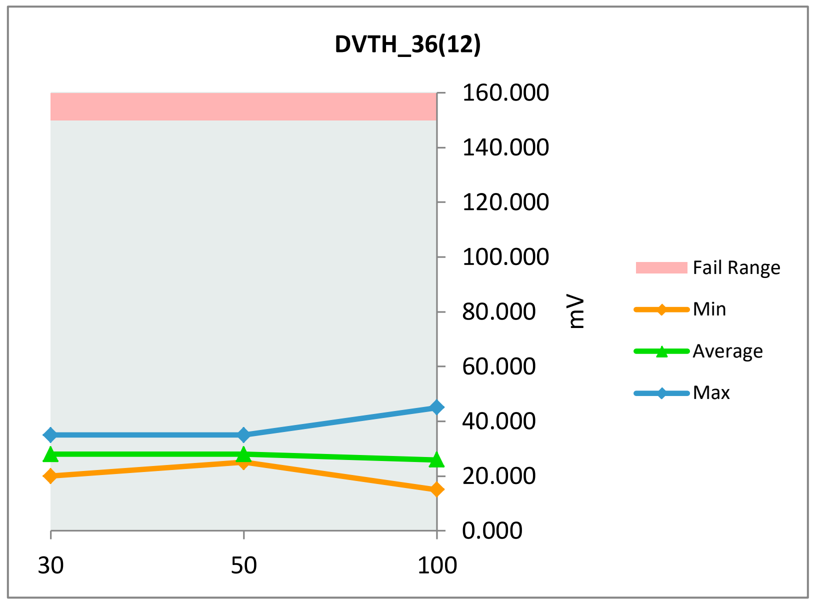


HDR TID Report T0 data
SN55LVCP22A-SP

		DVTH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	25.000	20.000	5.000
30	2	25.000	25.000	0.000
30	3	35.000	35.000	0.000
30	4	30.000	30.000	0.000
30	5	35.000	30.000	5.000
50	11	35.000	25.000	10.000
50	12	35.000	30.000	5.000
50	13	25.000	35.000	-10.000
50	14	25.000	25.000	0.000
50	15	35.000	25.000	10.000
100	22	15.000	15.000	0.000
100	23	30.000	30.000	0.000
100	24	15.000	25.000	-10.000
100	25	40.000	45.000	-5.000
100	26	25.000	25.000	0.000
100	27	40.000	45.000	-5.000
100	28	35.000	30.000	5.000
100	29	25.000	15.000	10.000
100	30	20.000	20.000	0.000
100	31	25.000	20.000	5.000
100	32	25.000	25.000	0.000
100	33	25.000	25.000	0.000
100	34	30.000	35.000	-5.000
100	35	30.000	30.000	0.000
100	36	20.000	25.000	-5.000
100	37	30.000	30.000	0.000
100	38	20.000	20.000	0.000
100	39	25.000	20.000	5.000
100	40	25.000	25.000	0.000
100	41	20.000	20.000	0.000
100	42	20.000	20.000	0.000
100	43	30.000	25.000	5.000
100	44	30.000	25.000	5.000
	Max	40.000	45.000	10.000
	Average	27.424	26.515	0.909
	Min	15.000	15.000	-10.000
	Std Dev	6.510	7.014	4.914

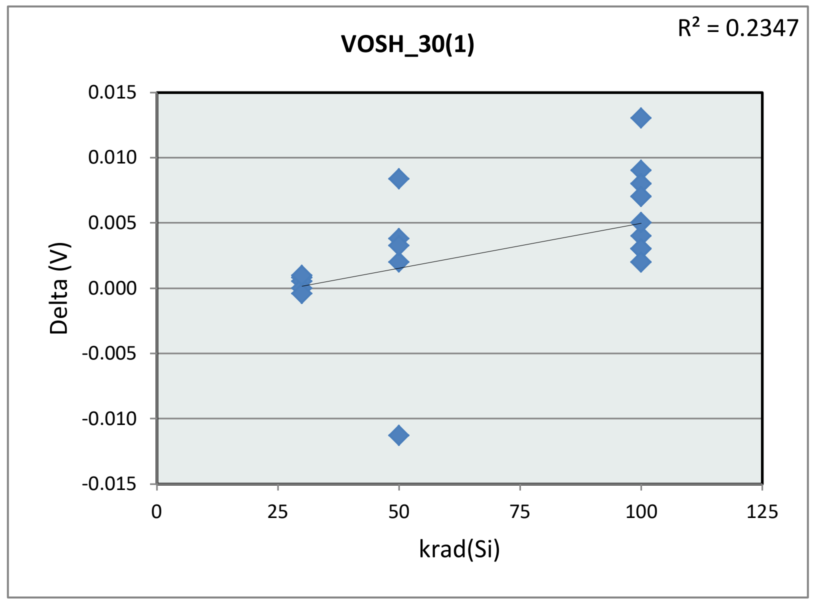


	DVTH_36(12)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	150	mV	
Min Limit		mV	
krad(Si)	30	50	100
LL			
Min	20.000	25.000	15.000
Average	28.000	28.000	25.870
Max	35.000	35.000	45.000
UL	150.000	150.000	150.000

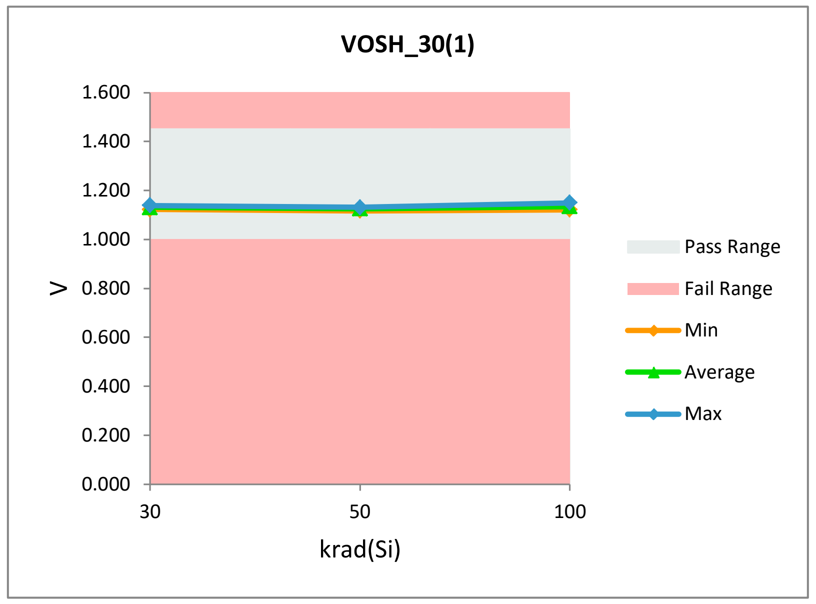


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.132	1.131	0.001
30	2	1.135	1.135	0.000
30	3	1.122	1.122	0.000
30	4	1.130	1.129	0.001
30	5	1.139	1.139	0.000
50	11	1.130	1.128	0.002
50	12	1.118	1.129	-0.011
50	13	1.121	1.117	0.004
50	14	1.134	1.131	0.003
50	15	1.129	1.121	0.008
100	22	1.136	1.129	0.007
100	23	1.139	1.131	0.008
100	24	1.148	1.143	0.005
100	25	1.137	1.132	0.005
100	26	1.137	1.134	0.003
100	27	1.129	1.126	0.003
100	28	1.148	1.145	0.003
100	29	1.128	1.125	0.003
100	30	1.148	1.145	0.003
100	31	1.144	1.142	0.002
100	32	1.143	1.140	0.003
100	33	1.140	1.138	0.002
100	34	1.140	1.127	0.013
100	35	1.132	1.124	0.008
100	36	1.139	1.130	0.009
100	37	1.145	1.137	0.008
100	38	1.156	1.149	0.007
100	39	1.150	1.143	0.007
100	40	1.133	1.129	0.004
100	41	1.126	1.121	0.005
100	42	1.133	1.130	0.003
100	43	1.139	1.137	0.002
100	44	1.139	1.137	0.002
	Max	1.156	1.149	0.013
	Average	1.136	1.133	0.004
	Min	1.118	1.117	-0.011
	Std Dev	0.009	0.008	0.004

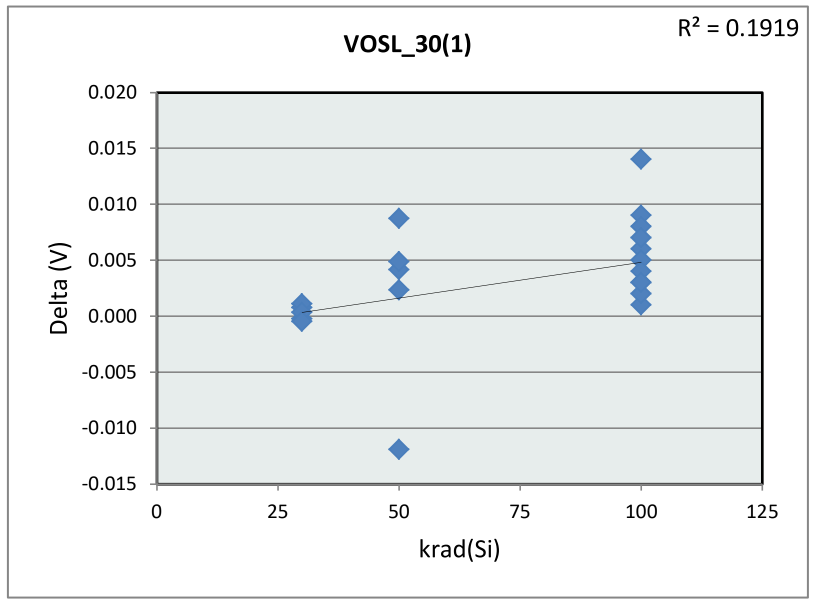


	VOSH_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.122	1.117	1.121
Average	1.131	1.125	1.135
Max	1.139	1.131	1.149
UL	1.450	1.450	1.450

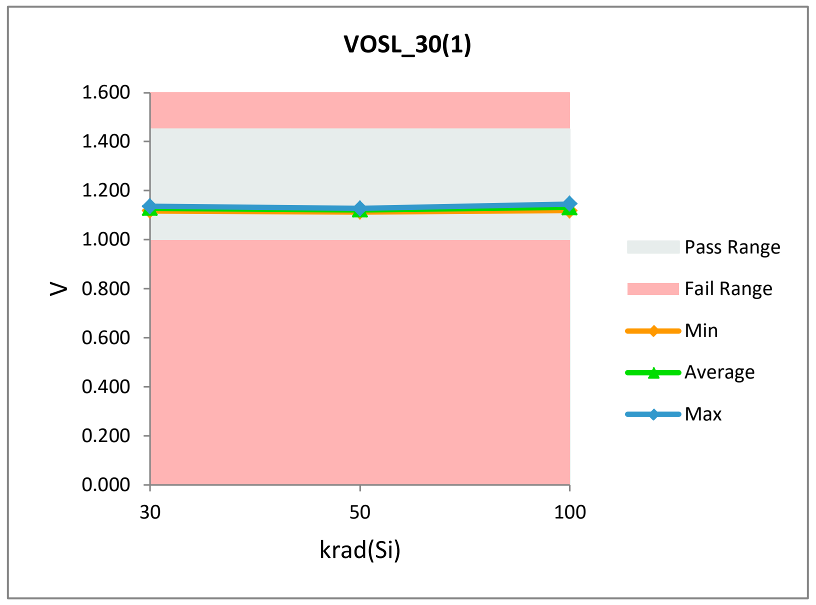


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	1.129	1.128	0.001
30	2	1.133	1.132	0.001
30	3	1.118	1.118	0.000
30	4	1.126	1.126	0.000
30	5	1.136	1.136	0.000
50	11	1.126	1.124	0.002
50	12	1.114	1.126	-0.012
50	13	1.117	1.113	0.004
50	14	1.132	1.127	0.005
50	15	1.126	1.117	0.009
100	22	1.132	1.126	0.006
100	23	1.135	1.128	0.007
100	24	1.145	1.140	0.005
100	25	1.134	1.129	0.005
100	26	1.133	1.131	0.002
100	27	1.125	1.122	0.003
100	28	1.144	1.141	0.003
100	29	1.124	1.121	0.003
100	30	1.145	1.142	0.003
100	31	1.140	1.139	0.001
100	32	1.140	1.137	0.003
100	33	1.137	1.135	0.002
100	34	1.137	1.123	0.014
100	35	1.129	1.121	0.008
100	36	1.136	1.127	0.009
100	37	1.143	1.135	0.008
100	38	1.153	1.146	0.007
100	39	1.147	1.140	0.007
100	40	1.129	1.126	0.003
100	41	1.123	1.119	0.004
100	42	1.130	1.128	0.002
100	43	1.136	1.133	0.003
100	44	1.136	1.133	0.003
	Max	1.153	1.146	0.014
	Average	1.133	1.129	0.004
	Min	1.114	1.113	-0.012
	Std Dev	0.009	0.008	0.004

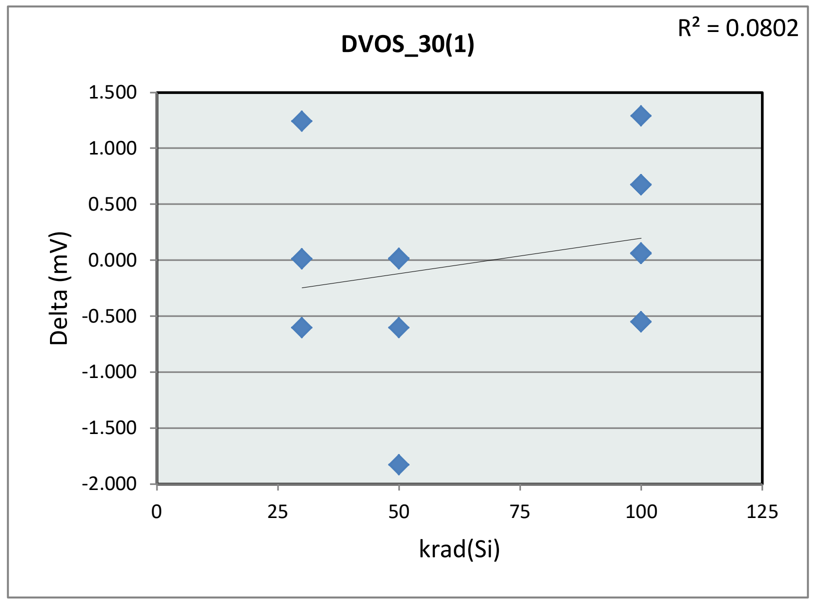


	VOSL_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.118	1.113	1.119
Average	1.128	1.121	1.131
Max	1.136	1.127	1.146
UL	1.450	1.450	1.450

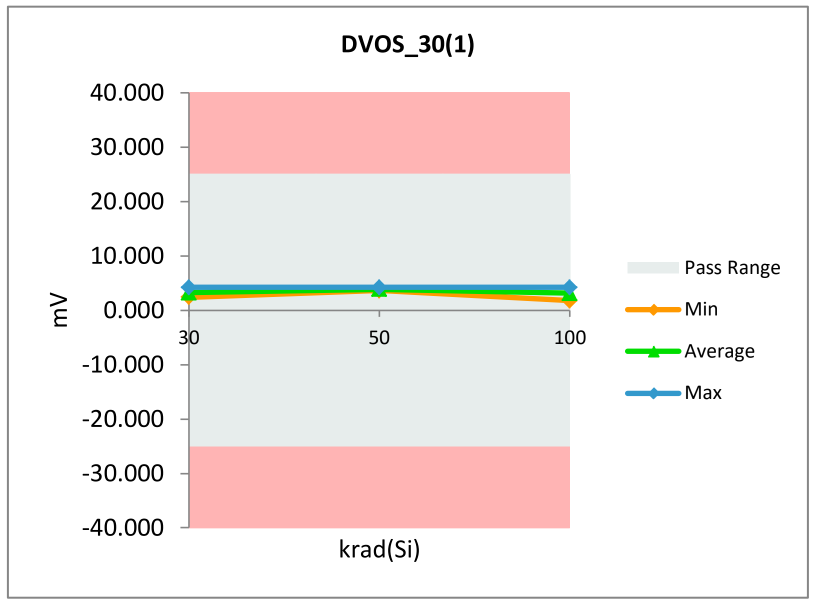


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOS_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	3.026	3.014	0.012
30	2	2.412	3.014	-0.602
30	3	4.252	4.240	0.012
30	4	3.639	2.401	1.238
30	5	3.026	3.628	-0.602
50	11	3.639	3.626	0.013
50	12	3.639	3.627	0.012
50	13	3.638	4.242	-0.604
50	14	2.411	4.241	-1.830
50	15	3.639	3.627	0.012
100	22	3.050	2.990	0.060
100	23	3.663	2.988	0.675
100	24	3.664	2.989	0.675
100	25	3.050	3.603	-0.553
100	26	3.664	2.990	0.674
100	27	4.891	4.217	0.674
100	28	4.277	4.217	0.060
100	29	3.664	3.604	0.060
100	30	3.050	2.991	0.059
100	31	3.664	2.991	0.673
100	32	3.050	2.990	0.060
100	33	3.050	3.604	-0.554
100	34	3.664	3.602	0.062
100	35	3.664	2.376	1.288
100	36	3.050	2.989	0.061
100	37	2.436	1.762	0.674
100	38	2.436	2.989	-0.553
100	39	3.050	2.992	0.058
100	40	4.278	3.605	0.673
100	41	3.050	2.378	0.672
100	42	3.050	2.379	0.671
100	43	3.050	3.604	-0.554
100	44	3.050	3.604	-0.554
	Max	4.891	4.242	1.288
	Average	3.359	3.276	0.082
	Min	2.411	1.762	-1.830
	Std Dev	0.577	0.619	0.639

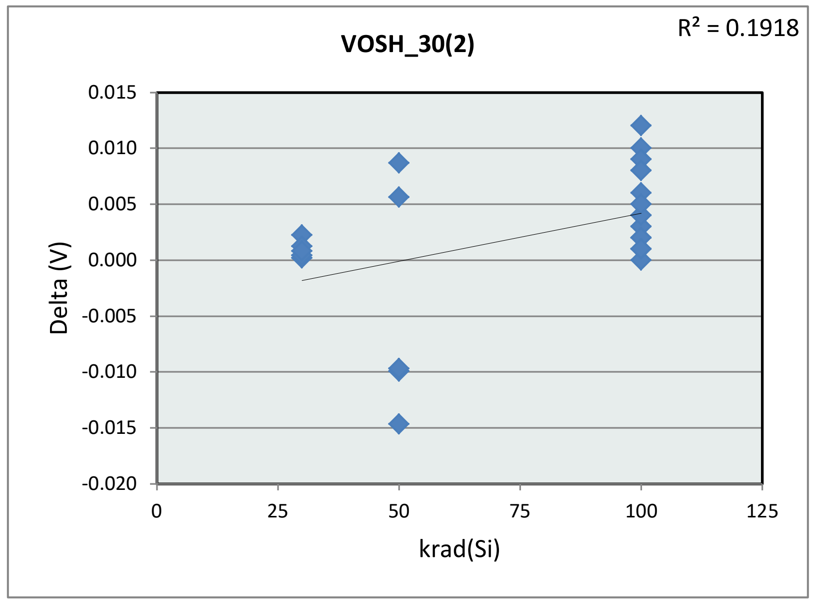


	DVOS_30(1)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	2.401	3.626	1.762
Average	3.259	3.873	3.150
Max	4.240	4.242	4.217
UL	25.000	25.000	25.000

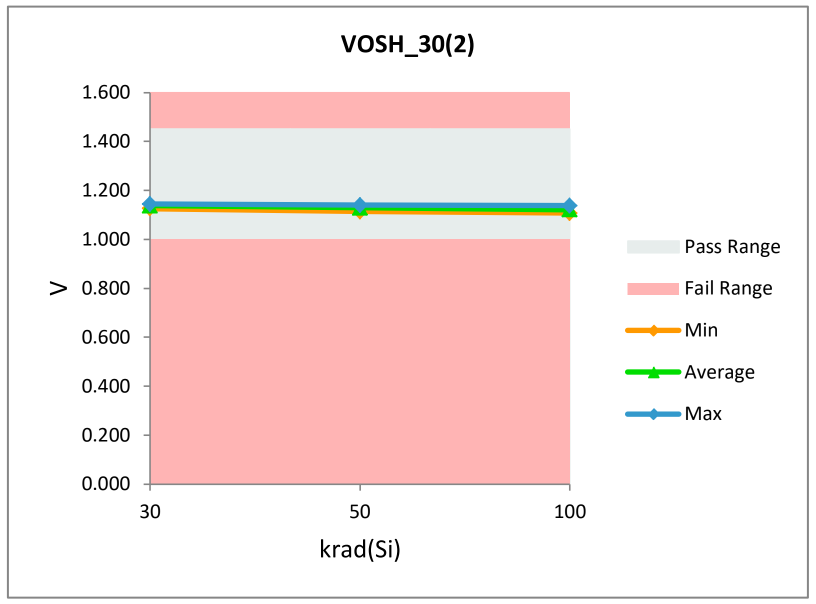


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	1.144	1.144	0.000
30	2	1.128	1.126	0.002
30	3	1.137	1.137	0.000
30	4	1.136	1.135	0.001
30	5	1.145	1.144	0.001
50	11	1.130	1.140	-0.010
50	12	1.139	1.130	0.009
50	13	1.123	1.138	-0.015
50	14	1.120	1.114	0.006
50	15	1.112	1.122	-0.010
100	22	1.125	1.119	0.006
100	23	1.118	1.108	0.010
100	24	1.122	1.118	0.004
100	25	1.130	1.125	0.005
100	26	1.122	1.120	0.002
100	27	1.127	1.124	0.003
100	28	1.126	1.124	0.002
100	29	1.129	1.125	0.004
100	30	1.121	1.118	0.003
100	31	1.133	1.129	0.004
100	32	1.127	1.125	0.002
100	33	1.119	1.119	0.000
100	34	1.119	1.107	0.012
100	35	1.143	1.134	0.009
100	36	1.116	1.107	0.009
100	37	1.119	1.111	0.008
100	38	1.121	1.113	0.008
100	39	1.142	1.137	0.005
100	40	1.138	1.137	0.001
100	41	1.127	1.125	0.002
100	42	1.124	1.123	0.001
100	43	1.123	1.122	0.001
100	44	1.123	1.122	0.001
	Max	1.145	1.144	0.012
	Average	1.128	1.125	0.003
	Min	1.112	1.107	-0.015
	Std Dev	0.009	0.010	0.006



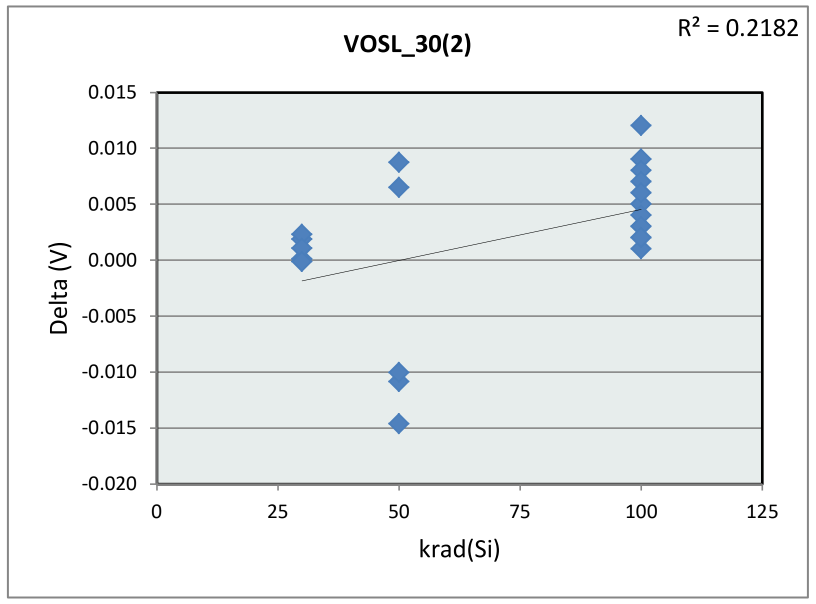
	VOSH_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.126	1.114	1.107
Average	1.137	1.129	1.121
Max	1.144	1.140	1.137
UL	1.450	1.450	1.450



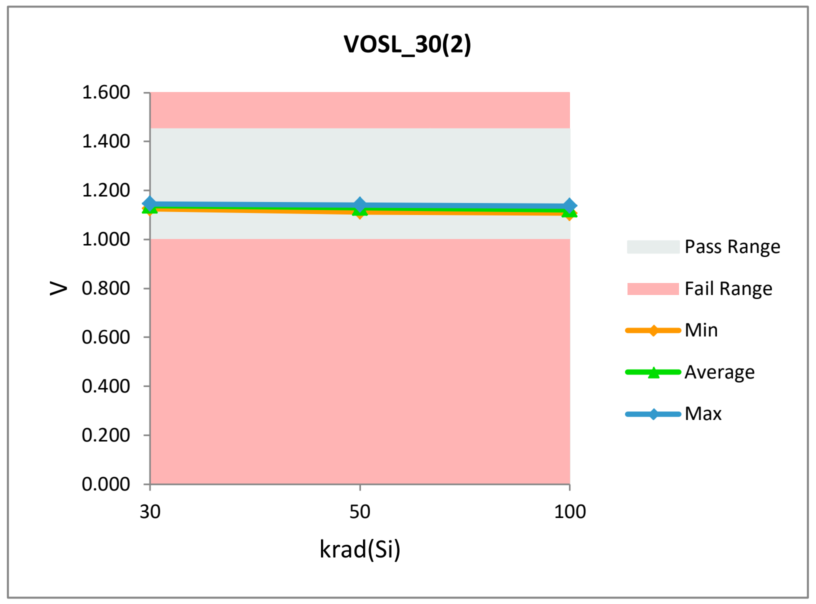
HDR TID Report T0 data
SN55LVCP22A-SP

	VOSL_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	1.145	1.143	0.002
30	2	1.128	1.126	0.002
30	3	1.138	1.138	0.000
30	4	1.135	1.134	0.001
30	5	1.145	1.145	0.000
50	11	1.130	1.141	-0.011
50	12	1.139	1.130	0.009
50	13	1.123	1.138	-0.015
50	14	1.118	1.112	0.006
50	15	1.113	1.123	-0.010
100	22	1.125	1.119	0.006
100	23	1.118	1.109	0.009
100	24	1.123	1.118	0.005
100	25	1.131	1.126	0.005
100	26	1.122	1.119	0.003
100	27	1.128	1.124	0.004
100	28	1.126	1.123	0.003
100	29	1.131	1.126	0.005
100	30	1.121	1.118	0.003
100	31	1.133	1.129	0.004
100	32	1.127	1.124	0.003
100	33	1.119	1.118	0.001
100	34	1.120	1.108	0.012
100	35	1.143	1.134	0.009
100	36	1.115	1.107	0.008
100	37	1.119	1.112	0.007
100	38	1.120	1.113	0.007
100	39	1.142	1.136	0.006
100	40	1.138	1.136	0.002
100	41	1.128	1.126	0.002
100	42	1.124	1.122	0.002
100	43	1.124	1.122	0.002
100	44	1.124	1.122	0.002
	Max	1.145	1.145	0.012
	Average	1.128	1.125	0.003
	Min	1.113	1.107	-0.015
	Std Dev	0.009	0.010	0.006

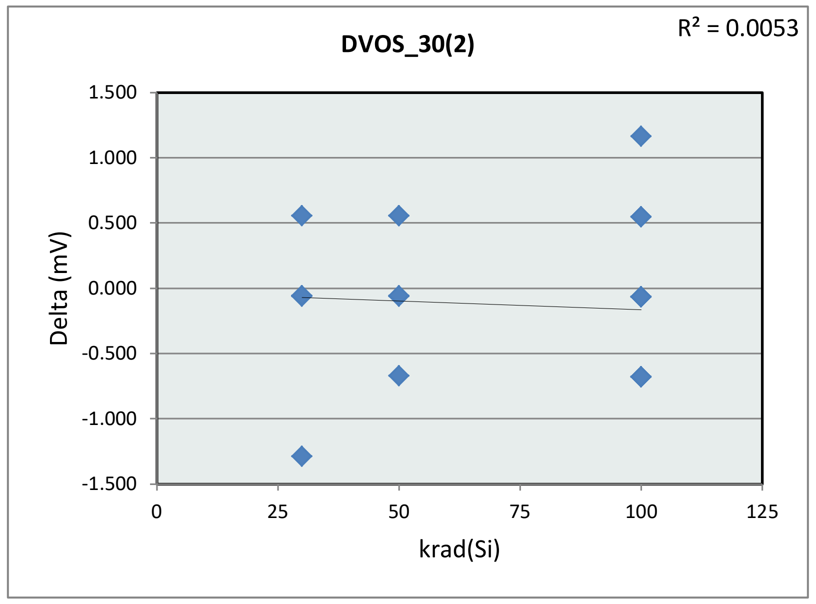


	VOSL_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.126	1.112	1.107
Average	1.137	1.129	1.121
Max	1.145	1.141	1.136
UL	1.450	1.450	1.450

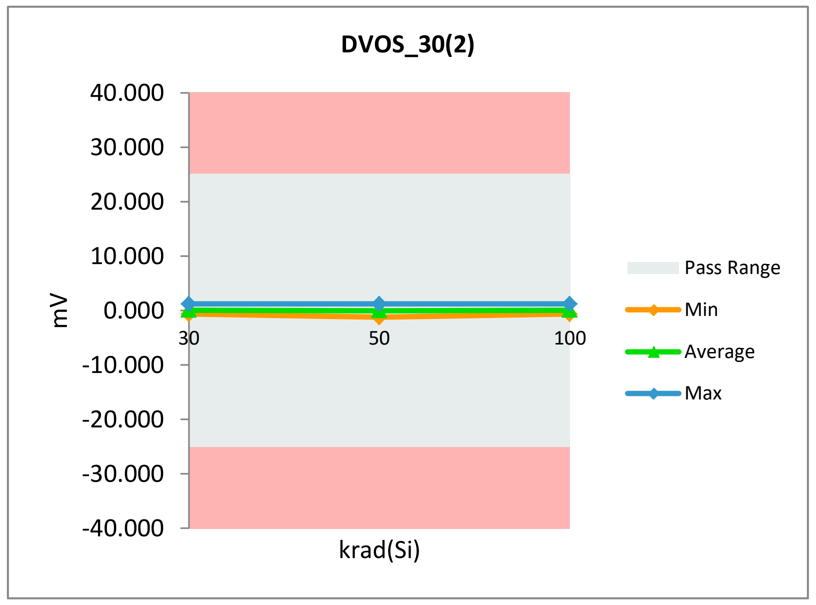


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOS_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	-0.676	0.611	-1.287
30	2	-0.063	-0.003	-0.060
30	3	-0.677	-0.616	-0.061
30	4	1.166	1.225	-0.059
30	5	-0.062	-0.616	0.554
50	11	-0.063	-0.616	0.553
50	12	-0.062	0.611	-0.673
50	13	-0.063	-0.002	-0.061
50	14	1.164	1.225	-0.061
50	15	-0.676	-1.230	0.554
100	22	-0.090	-0.024	-0.066
100	23	-0.093	-0.025	-0.068
100	24	-0.091	0.589	-0.680
100	25	-0.705	-0.638	-0.067
100	26	0.522	1.203	-0.681
100	27	-0.705	-0.024	-0.681
100	28	-0.092	0.589	-0.681
100	29	-1.318	-0.638	-0.680
100	30	-0.090	-0.637	0.548
100	31	-0.091	-0.024	-0.067
100	32	0.522	0.589	-0.067
100	33	0.522	0.589	-0.067
100	34	-0.705	-0.638	-0.067
100	35	-0.091	-0.025	-0.067
100	36	0.522	-0.025	0.547
100	37	0.523	-0.638	1.161
100	38	0.522	-0.025	0.547
100	39	0.524	1.203	-0.679
100	40	-0.090	0.590	-0.679
100	41	-0.705	-0.638	-0.067
100	42	0.524	0.590	-0.066
100	43	-0.705	-0.024	-0.681
100	44	-0.705	-0.024	-0.681
	Max	1.166	1.225	1.161
	Average	-0.064	0.075	-0.139
	Min	-1.318	-1.230	-1.287
	Std Dev	0.585	0.653	0.526

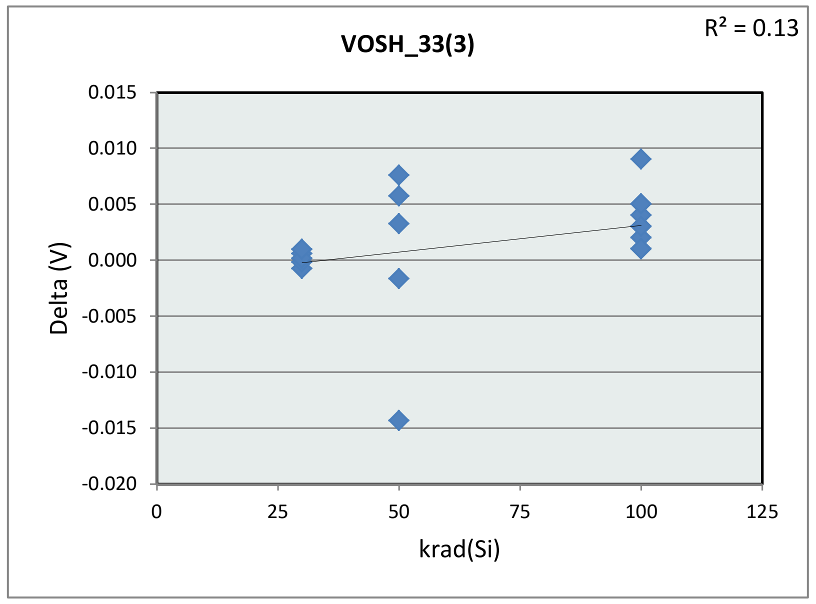


	DVOS_30(2)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-0.616	-1.230	-0.638
Average	0.120	-0.002	0.082
Max	1.225	1.225	1.203
UL	25.000	25.000	25.000

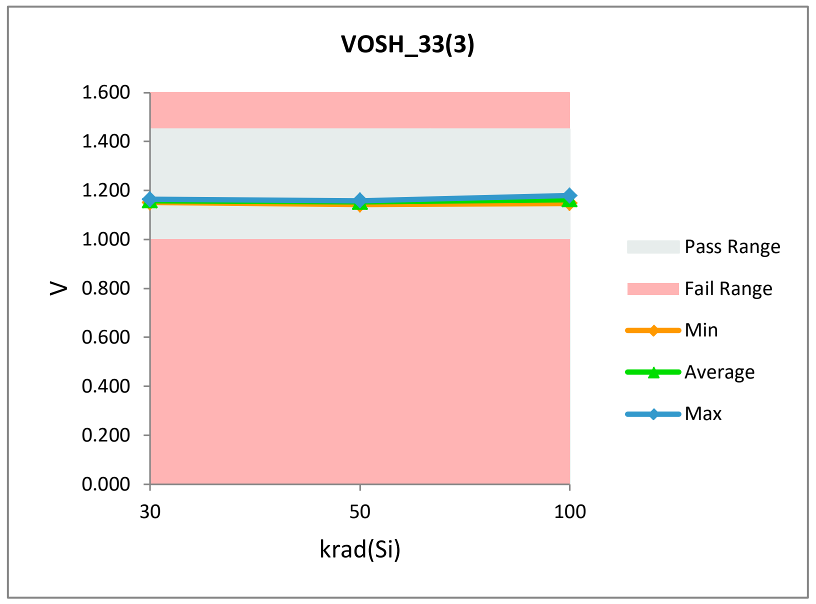


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSH_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.158	1.157	0.001
30	2	1.161	1.162	-0.001
30	3	1.151	1.151	0.000
30	4	1.155	1.155	0.000
30	5	1.165	1.164	0.001
50	11	1.156	1.158	-0.002
50	12	1.142	1.156	-0.014
50	13	1.150	1.142	0.008
50	14	1.161	1.158	0.003
50	15	1.156	1.150	0.006
100	22	1.161	1.156	0.005
100	23	1.167	1.164	0.003
100	24	1.176	1.173	0.003
100	25	1.165	1.160	0.005
100	26	1.163	1.160	0.003
100	27	1.157	1.156	0.001
100	28	1.177	1.175	0.002
100	29	1.151	1.148	0.003
100	30	1.174	1.171	0.003
100	31	1.168	1.166	0.002
100	32	1.169	1.167	0.002
100	33	1.168	1.167	0.001
100	34	1.167	1.158	0.009
100	35	1.158	1.153	0.005
100	36	1.169	1.164	0.005
100	37	1.172	1.168	0.004
100	38	1.183	1.179	0.004
100	39	1.173	1.168	0.005
100	40	1.156	1.155	0.001
100	41	1.150	1.147	0.003
100	42	1.155	1.154	0.001
100	43	1.165	1.164	0.001
100	44	1.165	1.164	0.001
	Max	1.183	1.179	0.009
	Average	1.163	1.160	0.002
	Min	1.142	1.142	-0.014
	Std Dev	0.009	0.008	0.004

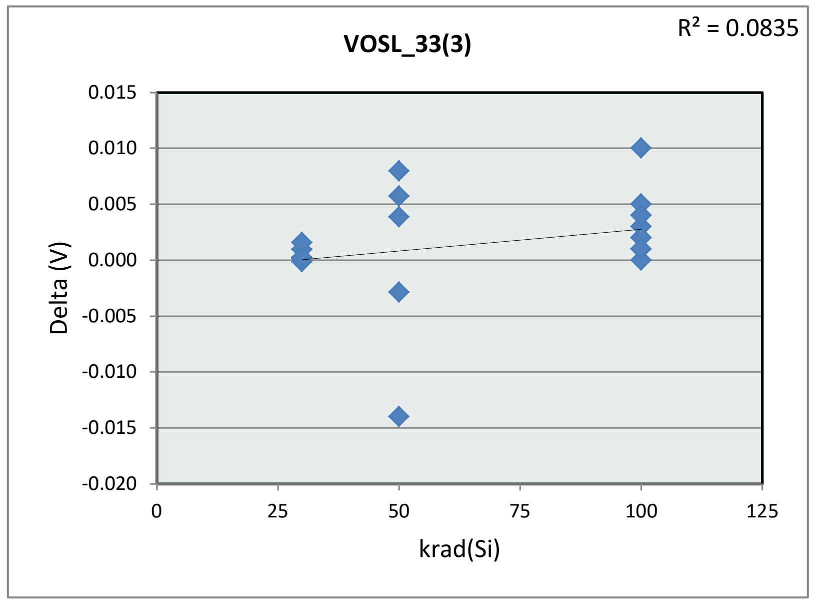


	VOSH_33(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.151	1.142	1.147
Average	1.158	1.153	1.162
Max	1.164	1.158	1.179
UL	1.450	1.450	1.450

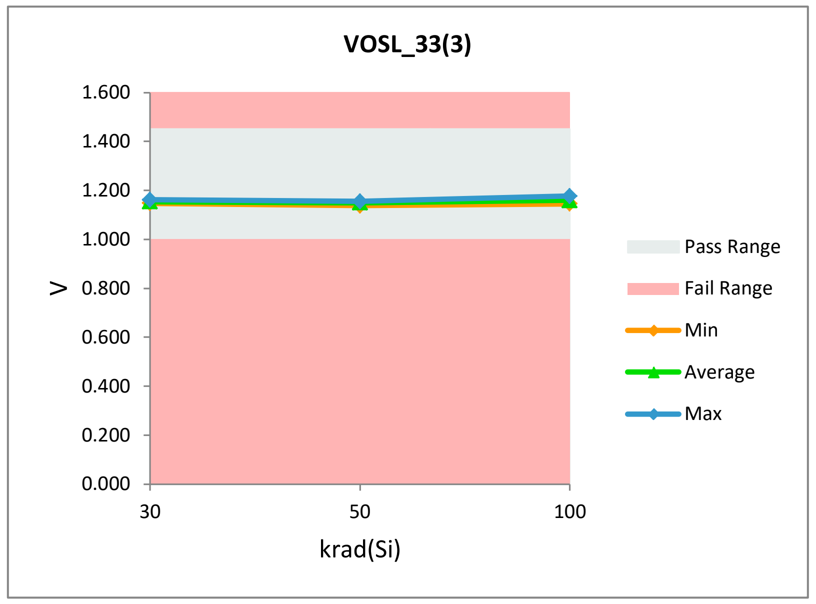


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSL_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.154	1.153	0.001
30	2	1.159	1.159	0.000
30	3	1.147	1.147	0.000
30	4	1.152	1.152	0.000
30	5	1.163	1.161	0.002
50	11	1.152	1.155	-0.003
50	12	1.138	1.152	-0.014
50	13	1.146	1.138	0.008
50	14	1.159	1.155	0.004
50	15	1.153	1.147	0.006
100	22	1.158	1.154	0.004
100	23	1.164	1.161	0.003
100	24	1.173	1.170	0.003
100	25	1.161	1.157	0.004
100	26	1.159	1.158	0.001
100	27	1.153	1.151	0.002
100	28	1.173	1.171	0.002
100	29	1.147	1.145	0.002
100	30	1.171	1.170	0.001
100	31	1.165	1.163	0.002
100	32	1.166	1.164	0.002
100	33	1.164	1.164	0.000
100	34	1.164	1.154	0.010
100	35	1.155	1.150	0.005
100	36	1.165	1.160	0.005
100	37	1.169	1.165	0.004
100	38	1.181	1.177	0.004
100	39	1.169	1.165	0.004
100	40	1.153	1.151	0.002
100	41	1.147	1.145	0.002
100	42	1.152	1.152	0.000
100	43	1.162	1.161	0.001
100	44	1.162	1.161	0.001
	Max	1.181	1.177	0.010
	Average	1.159	1.157	0.002
	Min	1.138	1.138	-0.014
	Std Dev	0.009	0.009	0.004

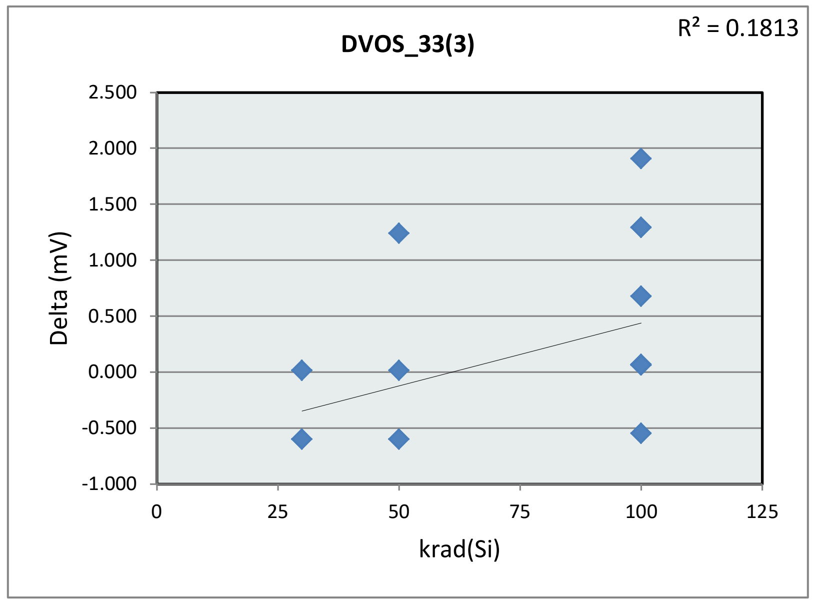


	VOSL_33(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.147	1.138	1.145
Average	1.154	1.149	1.160
Max	1.161	1.155	1.177
UL	1.450	1.450	1.450

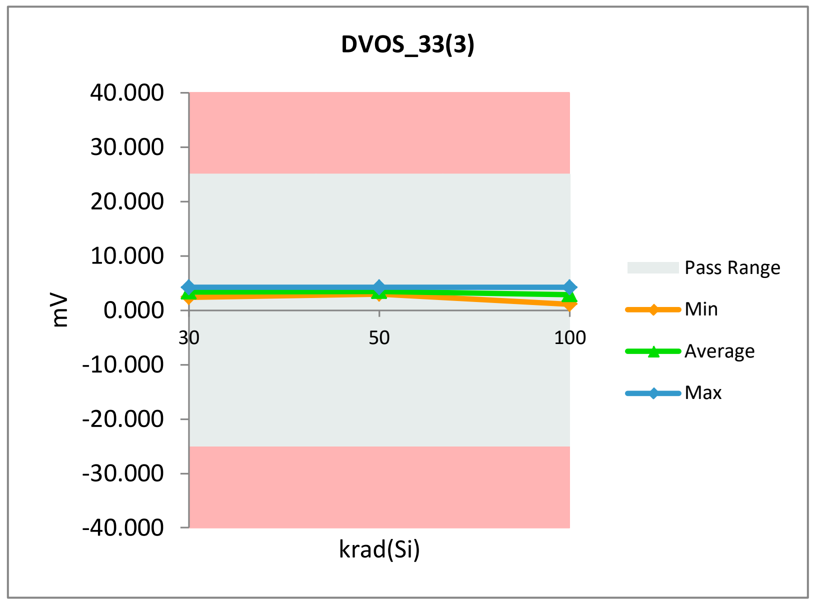


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOS_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	3.636	4.237	-0.601
30	2	2.409	2.397	0.012
30	3	3.636	4.237	-0.601
30	4	3.022	3.010	0.012
30	5	2.409	3.010	-0.601
50	11	4.250	3.010	1.240
50	12	3.636	3.624	0.012
50	13	3.636	4.238	-0.602
50	14	2.409	3.010	-0.601
50	15	3.023	3.624	-0.601
100	22	3.049	1.143	1.906
100	23	3.049	2.983	0.066
100	24	3.049	3.597	-0.548
100	25	4.276	2.984	1.292
100	26	3.662	2.371	1.291
100	27	3.662	4.212	-0.550
100	28	4.276	4.211	0.065
100	29	3.663	2.371	1.292
100	30	3.049	1.144	1.905
100	31	3.049	2.985	0.064
100	32	3.049	2.985	0.064
100	33	3.663	3.599	0.064
100	34	3.049	3.595	-0.546
100	35	3.049	2.983	0.066
100	36	3.662	3.597	0.065
100	37	3.049	2.983	0.066
100	38	2.435	1.756	0.679
100	39	3.662	2.985	0.677
100	40	3.663	3.599	0.064
100	41	3.049	2.372	0.677
100	42	3.049	1.759	1.290
100	43	3.049	2.985	0.064
100	44	3.049	2.985	0.064
	Max	4.276	4.238	1.906
	Average	3.283	3.048	0.235
	Min	2.409	1.143	-0.602
	Std Dev	0.508	0.821	0.753

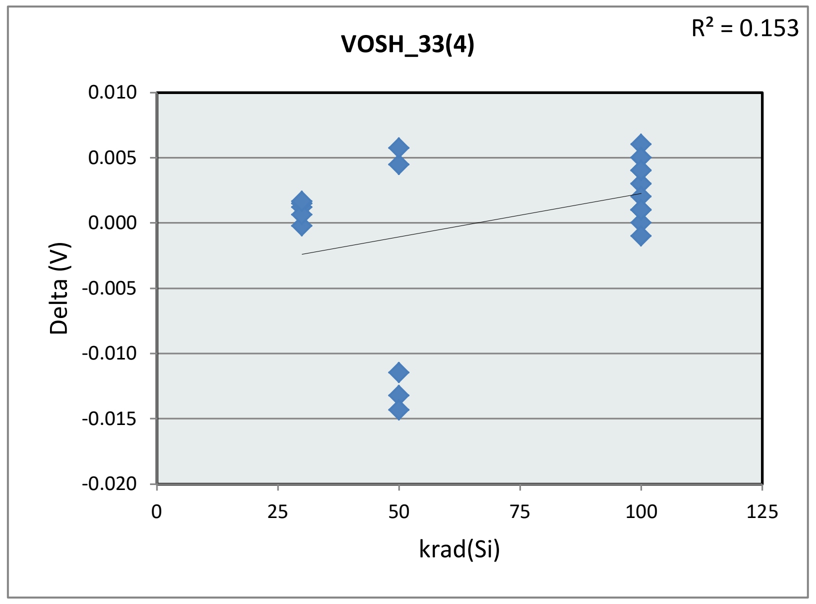


	DVOS_33(3)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	2.397	3.010	1.143
Average	3.378	3.501	2.878
Max	4.237	4.238	4.212
UL	25.000	25.000	25.000

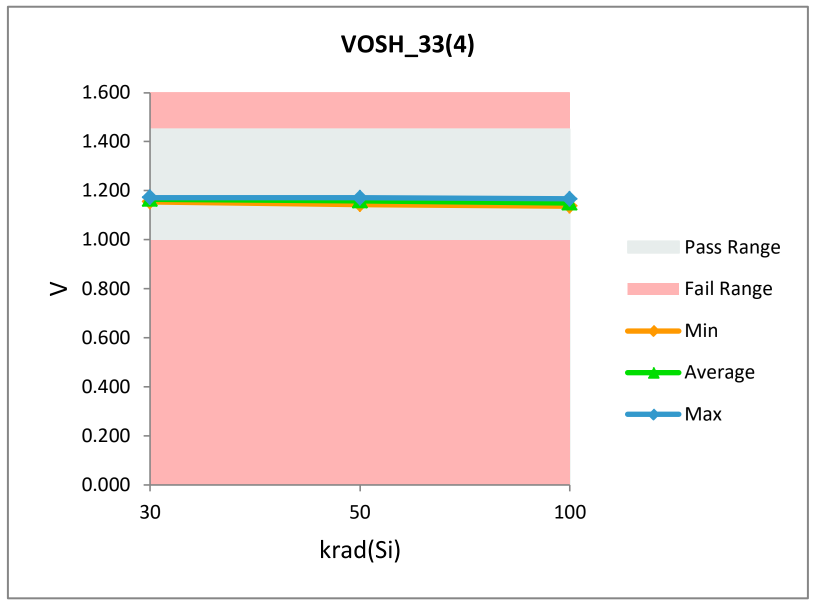


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSH_33(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal	Delta
30	1	1.171	1.170	0.001
30	2	1.156	1.155	0.001
30	3	1.169	1.169	0.000
30	4	1.163	1.162	0.001
30	5	1.174	1.172	0.002
50	11	1.160	1.171	-0.011
50	12	1.164	1.160	0.004
50	13	1.153	1.166	-0.013
50	14	1.150	1.144	0.006
50	15	1.139	1.153	-0.014
100	22	1.150	1.147	0.003
100	23	1.150	1.145	0.005
100	24	1.151	1.148	0.003
100	25	1.157	1.153	0.004
100	26	1.150	1.149	0.001
100	27	1.155	1.154	0.001
100	28	1.154	1.154	0.000
100	29	1.154	1.151	0.003
100	30	1.145	1.143	0.002
100	31	1.160	1.156	0.004
100	32	1.154	1.153	0.001
100	33	1.148	1.149	-0.001
100	34	1.145	1.139	0.006
100	35	1.170	1.166	0.004
100	36	1.142	1.137	0.005
100	37	1.145	1.141	0.004
100	38	1.148	1.143	0.005
100	39	1.166	1.162	0.004
100	40	1.163	1.162	0.001
100	41	1.153	1.152	0.001
100	42	1.149	1.148	0.001
100	43	1.149	1.148	0.001
100	44	1.149	1.148	0.001
	Max	1.174	1.172	0.006
	Average	1.155	1.154	0.001
	Min	1.139	1.137	-0.014
	Std Dev	0.009	0.010	0.005

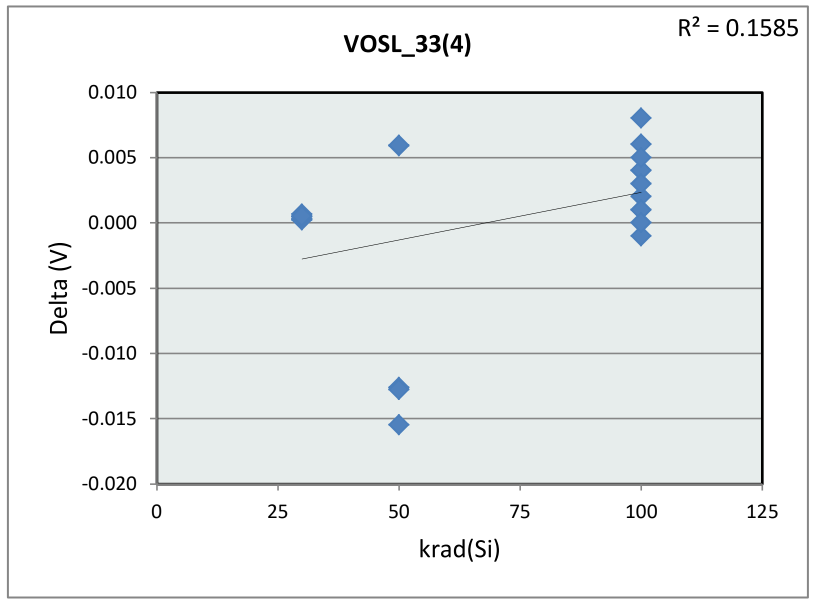


	VOSH_33(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.155	1.144	1.137
Average	1.166	1.159	1.150
Max	1.172	1.171	1.166
UL	1.450	1.450	1.450

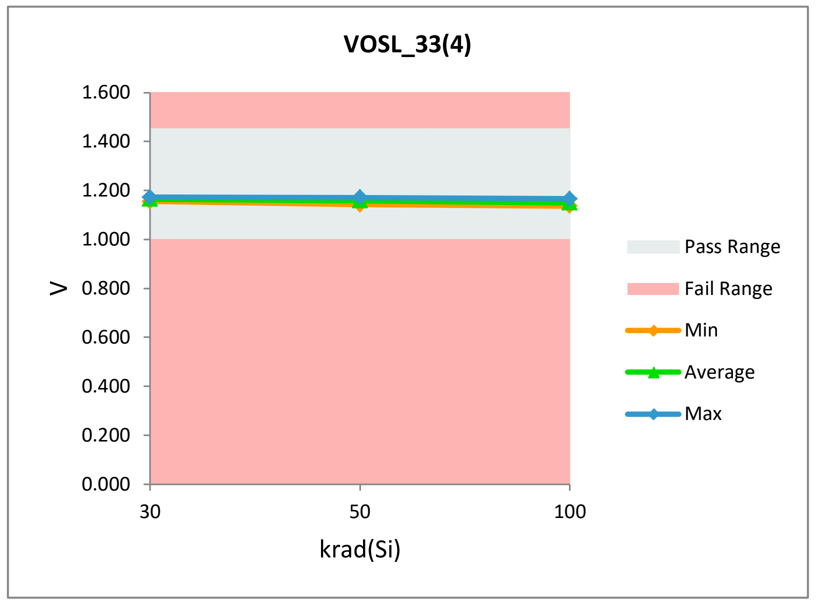


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSL_33(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.171	1.170	0.001
30	2	1.155	1.155	0.000
30	3	1.168	1.168	0.000
30	4	1.161	1.161	0.000
30	5	1.173	1.172	0.000
50	11	1.158	1.171	-0.013
50	12	1.164	1.158	0.006
50	13	1.152	1.165	-0.013
50	14	1.148	1.142	0.006
50	15	1.138	1.153	-0.015
100	22	1.150	1.146	0.004
100	23	1.150	1.144	0.006
100	24	1.150	1.147	0.003
100	25	1.157	1.153	0.004
100	26	1.149	1.147	0.002
100	27	1.154	1.153	0.001
100	28	1.153	1.152	0.001
100	29	1.154	1.150	0.004
100	30	1.143	1.142	0.001
100	31	1.159	1.156	0.003
100	32	1.153	1.153	0.000
100	33	1.148	1.148	0.000
100	34	1.145	1.137	0.008
100	35	1.170	1.166	0.004
100	36	1.142	1.136	0.006
100	37	1.144	1.140	0.004
100	38	1.147	1.142	0.005
100	39	1.164	1.161	0.003
100	40	1.162	1.163	-0.001
100	41	1.153	1.152	0.001
100	42	1.148	1.147	0.001
100	43	1.148	1.148	0.000
100	44	1.148	1.148	0.000
	Max	1.173	1.172	0.008
	Average	1.154	1.153	0.001
	Min	1.138	1.136	-0.015
	Std Dev	0.009	0.010	0.005

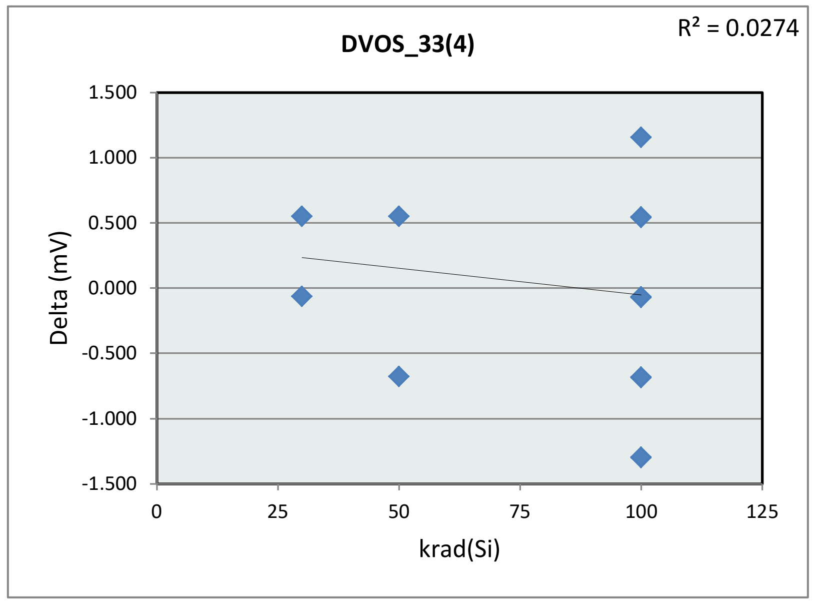


	VOSL_33(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.155	1.142	1.136
Average	1.165	1.158	1.149
Max	1.172	1.171	1.166
UL	1.450	1.450	1.450

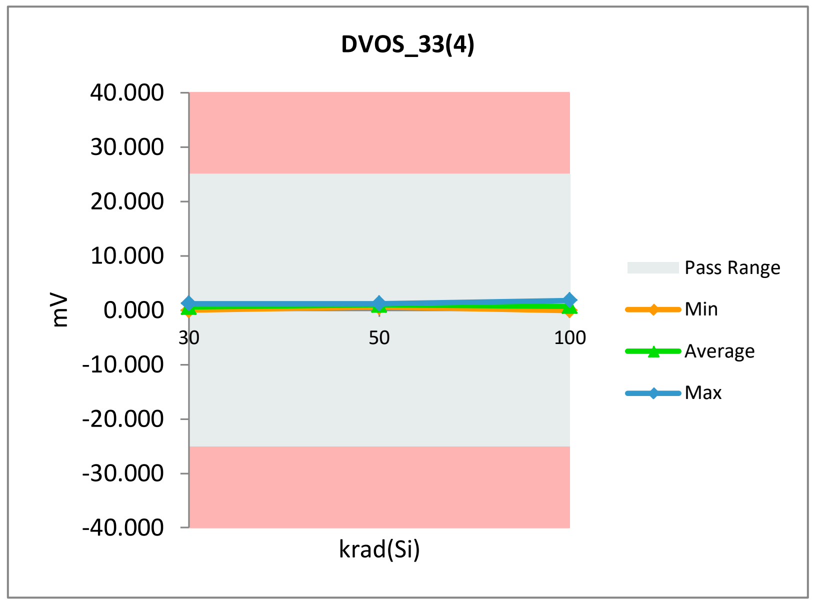


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOS_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	0.546	-0.003	0.549
30	2	1.161	0.611	0.550
30	3	0.546	0.611	-0.065
30	4	1.160	1.225	-0.065
30	5	1.160	0.611	0.549
50	11	1.161	0.611	0.550
50	12	0.546	1.225	-0.679
50	13	0.547	1.225	-0.678
50	14	1.775	1.225	0.550
50	15	1.161	0.611	0.550
100	22	0.516	1.201	-0.685
100	23	0.517	0.587	-0.071
100	24	1.129	1.201	-0.072
100	25	0.515	-0.026	0.541
100	26	1.129	1.814	-0.685
100	27	0.515	0.587	-0.072
100	28	0.515	1.814	-1.299
100	29	-0.098	0.587	-0.686
100	30	1.130	1.201	-0.071
100	31	0.515	-0.026	0.542
100	32	1.129	-0.026	1.155
100	33	0.517	0.588	-0.071
100	34	0.515	1.814	-1.299
100	35	-0.099	0.587	-0.686
100	36	-0.098	1.200	-1.298
100	37	0.516	1.200	-0.684
100	38	1.131	0.587	0.544
100	39	1.743	1.814	-0.071
100	40	0.516	-0.026	0.542
100	41	0.516	-0.026	0.542
100	42	1.130	0.587	0.543
100	43	1.129	-0.026	1.155
100	44	1.129	-0.026	1.155
	Max	1.775	1.814	1.155
	Average	0.785	0.762	0.024
	Min	-0.099	-0.026	-1.299
	Std Dev	0.465	0.600	0.706

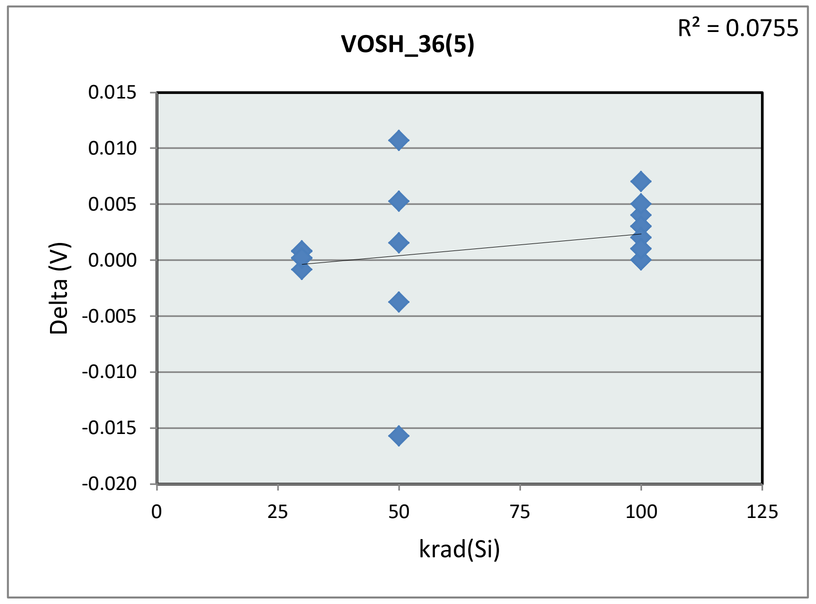


	DVOS_33(4)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	-0.003	0.611	-0.026
Average	0.611	0.979	0.747
Max	1.225	1.225	1.814
UL	25.000	25.000	25.000

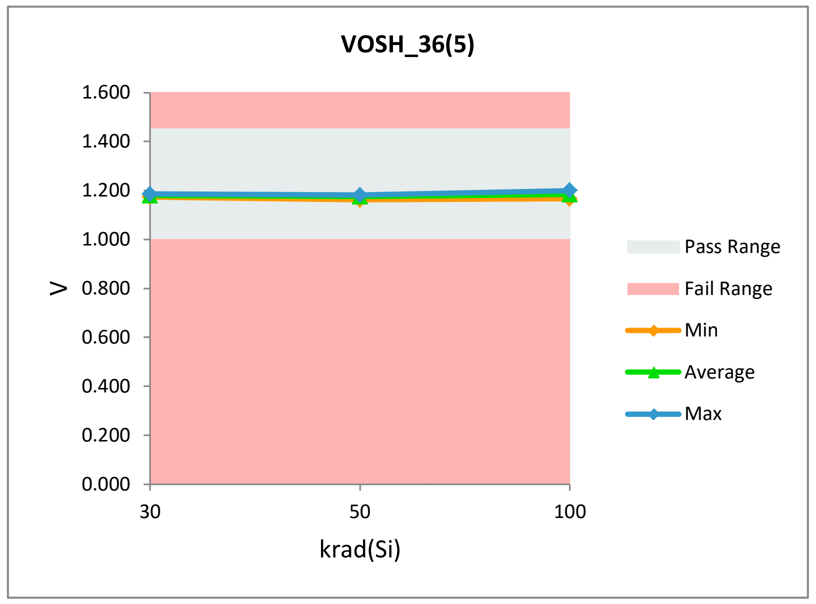


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSH_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.178	1.177	0.001
30	2	1.182	1.183	-0.001
30	3	1.174	1.174	0.000
30	4	1.175	1.174	0.001
30	5	1.185	1.185	0.000
50	11	1.177	1.181	-0.004
50	12	1.161	1.177	-0.016
50	13	1.172	1.161	0.011
50	14	1.182	1.180	0.002
50	15	1.177	1.172	0.005
100	22	1.181	1.177	0.004
100	23	1.188	1.186	0.002
100	24	1.198	1.195	0.003
100	25	1.184	1.181	0.003
100	26	1.183	1.182	0.001
100	27	1.178	1.178	0.000
100	28	1.198	1.197	0.001
100	29	1.167	1.167	0.000
100	30	1.194	1.191	0.003
100	31	1.186	1.185	0.001
100	32	1.190	1.188	0.002
100	33	1.188	1.188	0.000
100	34	1.186	1.179	0.007
100	35	1.176	1.173	0.003
100	36	1.191	1.187	0.004
100	37	1.192	1.189	0.003
100	38	1.203	1.200	0.003
100	39	1.191	1.186	0.005
100	40	1.176	1.173	0.003
100	41	1.169	1.166	0.003
100	42	1.174	1.172	0.002
100	43	1.184	1.183	0.001
100	44	1.184	1.183	0.001
	Max	1.203	1.200	0.011
	Average	1.183	1.181	0.002
	Min	1.161	1.161	-0.016
	Std Dev	0.009	0.009	0.004

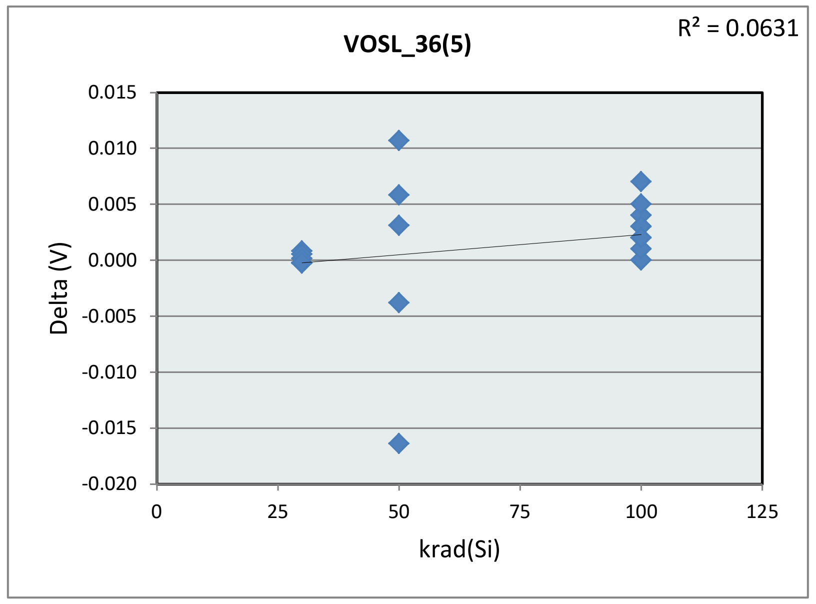


	VOSH_36(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.174	1.161	1.166
Average	1.179	1.174	1.183
Max	1.185	1.181	1.200
UL	1.450	1.450	1.450

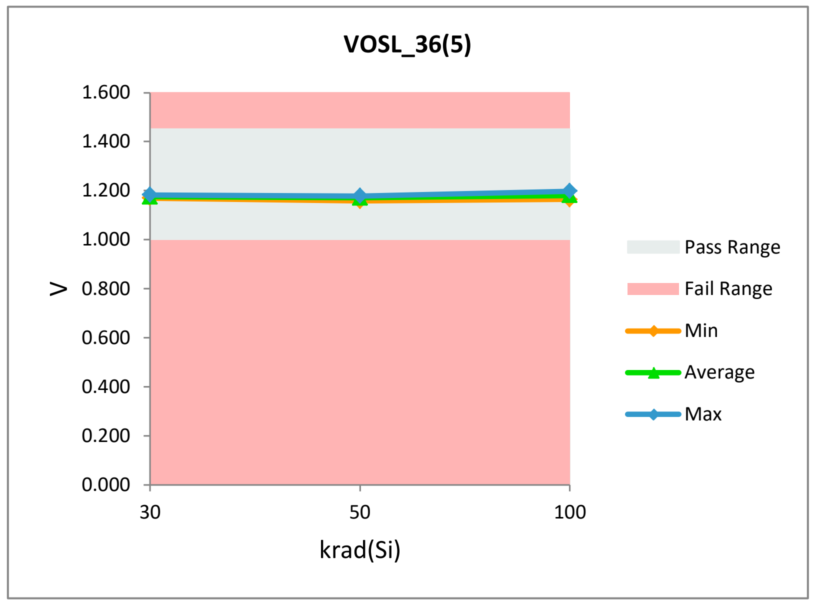


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSL_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.175	1.174	0.001
30	2	1.180	1.180	0.000
30	3	1.171	1.170	0.001
30	4	1.171	1.171	0.000
30	5	1.183	1.183	0.000
50	11	1.174	1.178	-0.004
50	12	1.158	1.174	-0.016
50	13	1.169	1.158	0.011
50	14	1.179	1.176	0.003
50	15	1.175	1.169	0.006
100	22	1.179	1.175	0.004
100	23	1.186	1.183	0.003
100	24	1.194	1.192	0.002
100	25	1.181	1.178	0.003
100	26	1.180	1.180	0.000
100	27	1.175	1.175	0.000
100	28	1.194	1.193	0.001
100	29	1.166	1.164	0.002
100	30	1.191	1.189	0.002
100	31	1.183	1.183	0.000
100	32	1.186	1.185	0.001
100	33	1.185	1.185	0.000
100	34	1.183	1.176	0.007
100	35	1.174	1.170	0.004
100	36	1.188	1.185	0.003
100	37	1.190	1.186	0.004
100	38	1.201	1.198	0.003
100	39	1.188	1.183	0.005
100	40	1.172	1.170	0.002
100	41	1.167	1.164	0.003
100	42	1.171	1.170	0.001
100	43	1.182	1.180	0.002
100	44	1.182	1.180	0.002
	Max	1.201	1.198	0.011
	Average	1.180	1.178	0.002
	Min	1.158	1.158	-0.016
	Std Dev	0.009	0.009	0.004

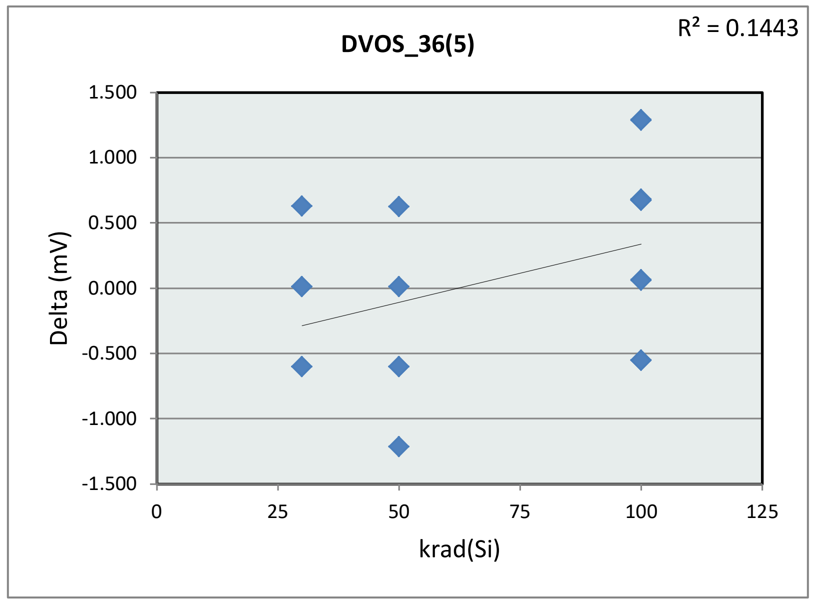


	VOSL_36(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.170	1.158	1.164
Average	1.176	1.171	1.180
Max	1.183	1.178	1.198
UL	1.450	1.450	1.450

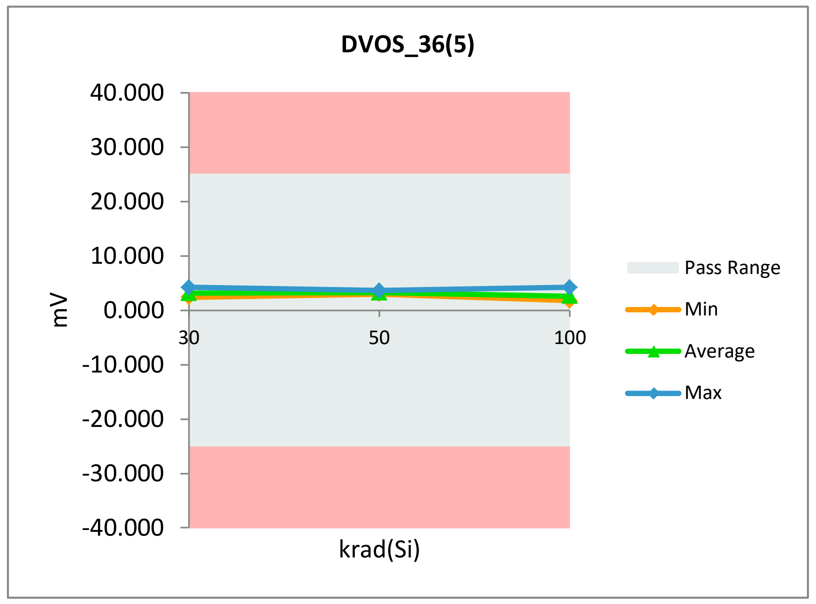


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOS_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	3.026	3.628	-0.602
30	2	2.413	2.402	0.011
30	3	3.640	4.242	-0.602
30	4	3.639	3.013	0.626
30	5	2.412	2.400	0.012
50	11	3.027	3.015	0.012
50	12	3.640	3.016	0.624
50	13	3.027	3.628	-0.601
50	14	2.413	3.629	-1.216
50	15	2.413	3.015	-0.602
100	22	2.437	1.761	0.676
100	23	2.437	2.989	-0.552
100	24	3.664	2.988	0.676
100	25	3.050	2.376	0.674
100	26	3.050	2.377	0.673
100	27	3.664	2.991	0.673
100	28	4.277	4.217	0.060
100	29	1.823	2.377	-0.554
100	30	2.436	1.762	0.674
100	31	3.664	2.376	1.288
100	32	3.664	2.990	0.674
100	33	3.664	2.379	1.285
100	34	3.664	2.985	0.679
100	35	2.436	2.987	-0.551
100	36	3.050	2.375	0.675
100	37	2.437	2.374	0.063
100	38	2.437	1.761	0.676
100	39	3.050	2.989	0.061
100	40	3.664	2.990	0.674
100	41	1.823	2.378	-0.555
100	42	3.050	1.763	1.287
100	43	2.437	2.990	-0.553
100	44	2.437	2.990	-0.553
	Max	4.277	4.242	1.288
	Average	2.969	2.793	0.176
	Min	1.823	1.761	-1.216
	Std Dev	0.628	0.631	0.673

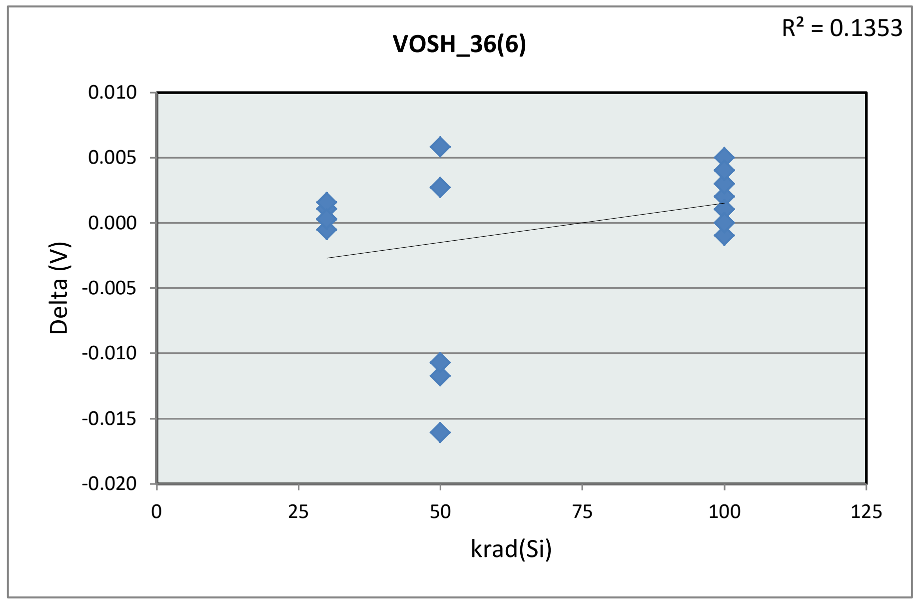


	DVOS_36(5)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	2.400	3.015	1.761
Average	3.137	3.261	2.616
Max	4.242	3.629	4.217
UL	25.000	25.000	25.000

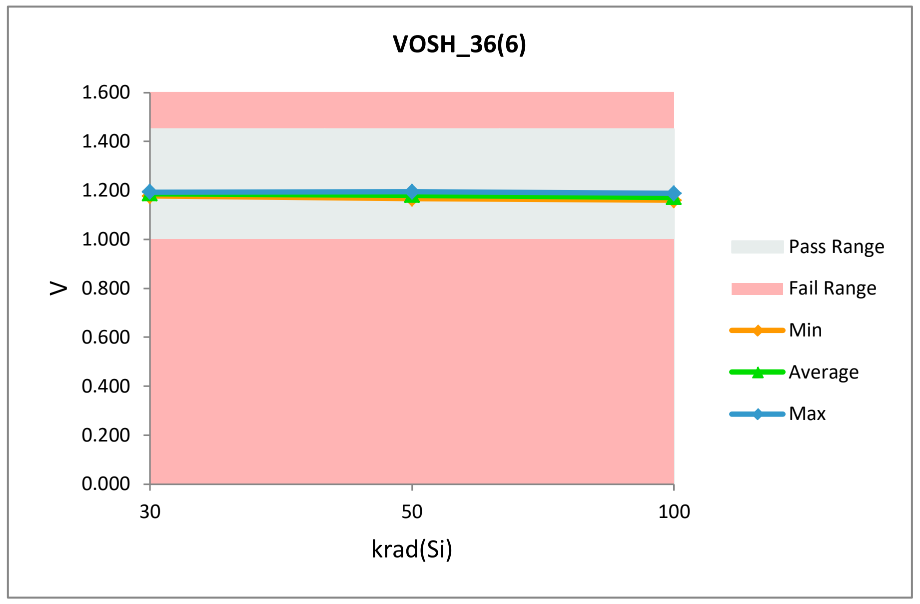


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSH_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal b	Delta
30	1	1.192	1.191	0.001
30	2	1.179	1.177	0.002
30	3	1.191	1.192	-0.001
30	4	1.182	1.182	0.000
30	5	1.193	1.193	0.000
50	11	1.182	1.194	-0.012
50	12	1.185	1.182	0.003
50	13	1.174	1.185	-0.011
50	14	1.172	1.166	0.006
50	15	1.159	1.175	-0.016
100	22	1.169	1.167	0.002
100	23	1.174	1.169	0.005
100	24	1.172	1.171	0.001
100	25	1.177	1.174	0.003
100	26	1.172	1.171	0.001
100	27	1.176	1.177	-0.001
100	28	1.175	1.175	0.000
100	29	1.173	1.170	0.003
100	30	1.164	1.162	0.002
100	31	1.179	1.177	0.002
100	32	1.175	1.175	0.000
100	33	1.170	1.170	0.000
100	34	1.165	1.161	0.004
100	35	1.191	1.188	0.003
100	36	1.163	1.159	0.004
100	37	1.165	1.162	0.003
100	38	1.169	1.165	0.004
100	39	1.186	1.182	0.004
100	40	1.183	1.182	0.001
100	41	1.173	1.173	0.000
100	42	1.167	1.167	0.000
100	43	1.168	1.168	0.000
100	44	1.168	1.168	0.000
	Max	1.193	1.194	0.006
	Average	1.175	1.175	0.000
	Min	1.159	1.159	-0.016
	Std Dev	0.009	0.010	0.005

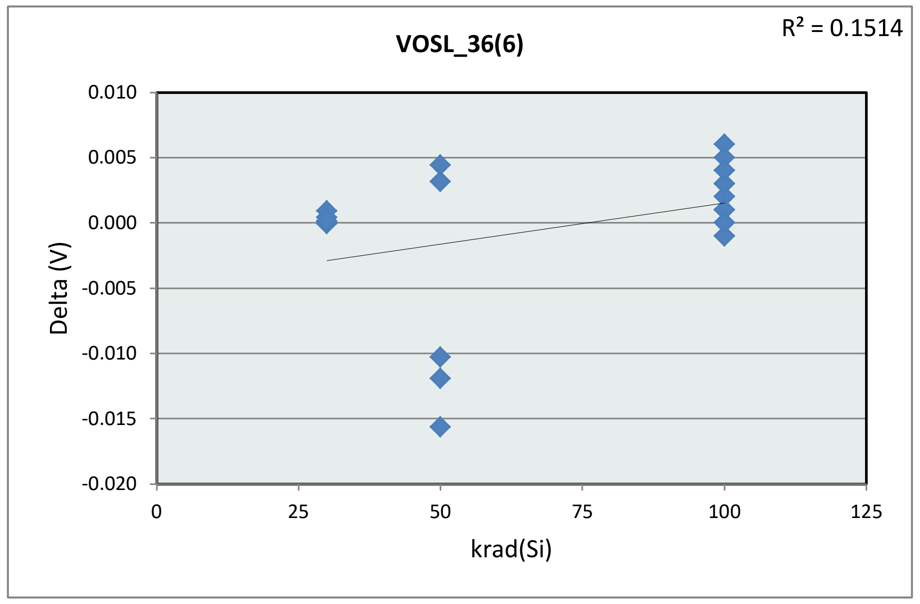


	VOSH_36(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.177	1.166	1.159
Average	1.187	1.180	1.171
Max	1.193	1.194	1.188
UL	1.450	1.450	1.450

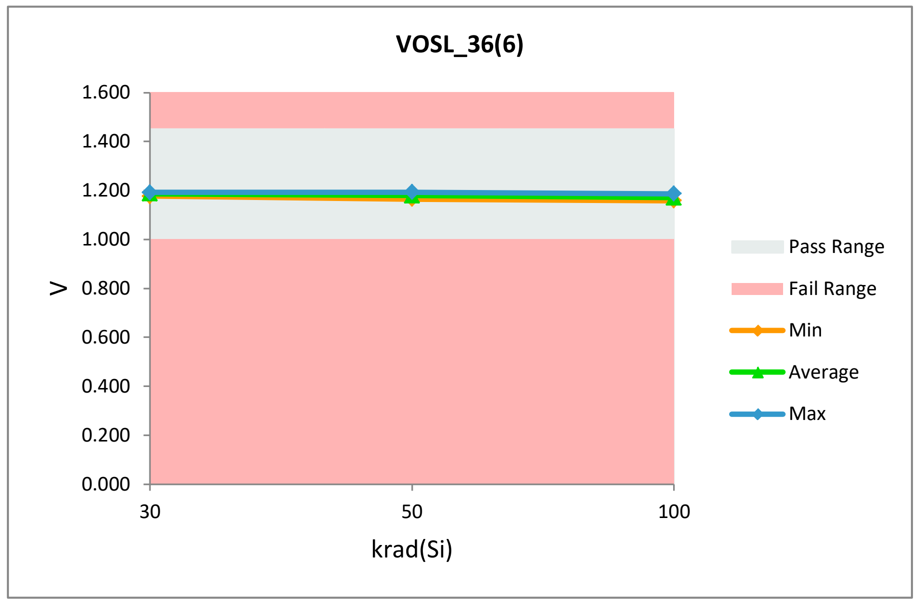


HDR TID Report T0 data
SN55LVCP22A-SP

		VOSL_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (anneal t	Delta
30	1	1.191	1.190	0.001
30	2	1.177	1.177	0.000
30	3	1.191	1.191	0.000
30	4	1.181	1.181	0.000
30	5	1.192	1.192	0.000
50	11	1.181	1.193	-0.012
50	12	1.184	1.181	0.003
50	13	1.174	1.184	-0.010
50	14	1.169	1.165	0.004
50	15	1.158	1.174	-0.016
100	22	1.168	1.166	0.002
100	23	1.174	1.168	0.006
100	24	1.171	1.169	0.002
100	25	1.177	1.174	0.003
100	26	1.170	1.170	0.000
100	27	1.176	1.175	0.001
100	28	1.174	1.173	0.001
100	29	1.173	1.170	0.003
100	30	1.162	1.161	0.001
100	31	1.178	1.176	0.002
100	32	1.175	1.175	0.000
100	33	1.169	1.170	-0.001
100	34	1.164	1.159	0.005
100	35	1.190	1.187	0.003
100	36	1.162	1.158	0.004
100	37	1.164	1.161	0.003
100	38	1.167	1.164	0.003
100	39	1.184	1.180	0.004
100	40	1.181	1.182	-0.001
100	41	1.172	1.173	-0.001
100	42	1.167	1.166	0.001
100	43	1.167	1.167	0.000
100	44	1.167	1.167	0.000
	Max	1.192	1.193	0.006
	Average	1.174	1.174	0.000
	Min	1.158	1.158	-0.016
	Std Dev	0.009	0.010	0.005

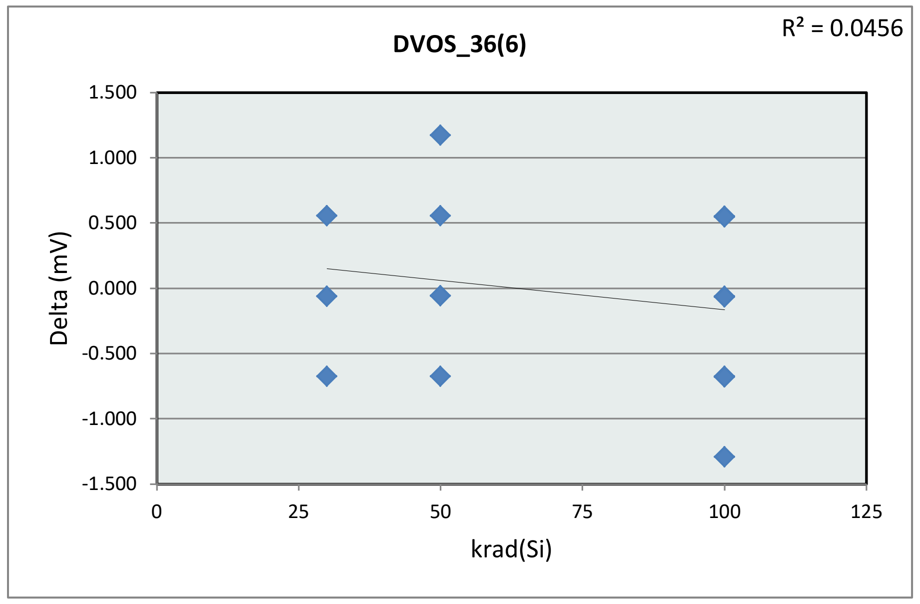


	VOSL_36(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	1.45	V	
Min Limit	1	V	
krad(Si)	30	50	100
LL	1.000	1.000	1.000
Min	1.177	1.165	1.158
Average	1.186	1.179	1.170
Max	1.192	1.193	1.187
UL	1.450	1.450	1.450

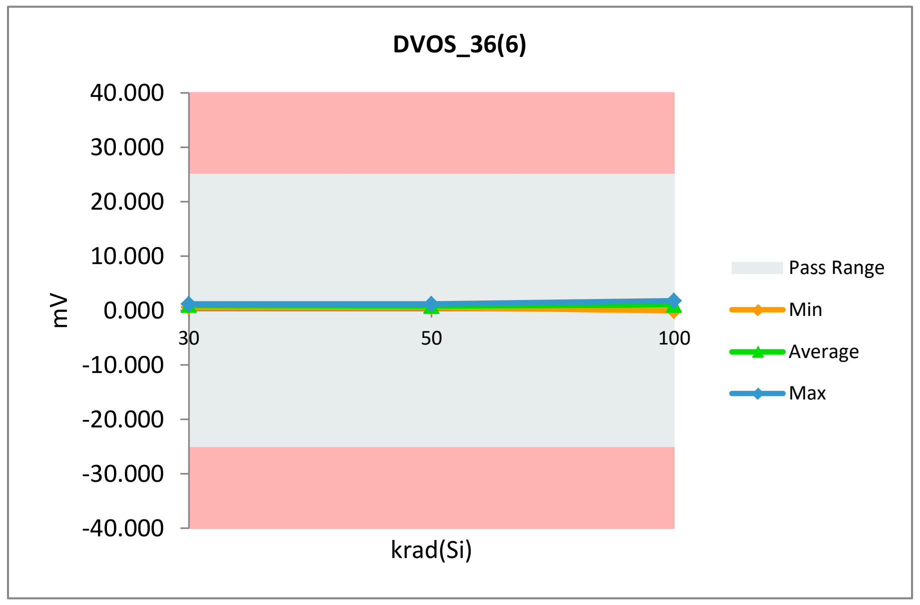


HDR TID Report T0 data
SN55LVCP22A-SP

		DVOS_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	ost Test (anneal t	Delta
30	1	1.164	0.611	0.553
30	2	1.167	0.611	0.556
30	3	0.550	1.225	-0.675
30	4	1.164	1.225	-0.061
30	5	1.164	1.225	-0.061
50	11	1.166	0.611	0.555
50	12	0.550	1.225	-0.675
50	13	0.552	0.611	-0.059
50	14	2.395	1.225	1.170
50	15	0.552	0.611	-0.059
100	22	1.136	1.816	-0.680
100	23	0.526	1.203	-0.677
100	24	1.137	1.816	-0.679
100	25	0.522	0.589	-0.067
100	26	1.751	1.203	0.548
100	27	0.522	1.816	-1.294
100	28	1.136	1.816	-0.680
100	29	-0.091	0.589	-0.680
100	30	1.749	1.202	0.547
100	31	1.136	0.589	0.547
100	32	0.523	0.589	-0.066
100	33	0.527	-0.023	0.550
100	34	0.522	1.201	-0.679
100	35	0.520	1.201	-0.681
100	36	1.137	0.589	0.548
100	37	1.137	1.202	-0.065
100	38	1.140	1.203	-0.063
100	39	1.748	1.815	-0.067
100	40	1.135	0.589	0.546
100	41	0.523	-0.025	0.548
100	42	0.522	1.816	-1.294
100	43	0.522	0.589	-0.067
100	44	0.522	0.589	-0.067
	Max	2.395	1.816	1.170
	Average	0.922	1.005	-0.083
	Min	-0.091	-0.025	-1.294
	Std Dev	0.507	0.523	0.605



	DVOS_36(6)		
Test Site	SLL LAB		
Tester	IMP		
Test Number	I2107203		
Max Limit	25	mV	
Min Limit	-25	mV	
krad(Si)	30	50	100
LL	-25.000	-25.000	-25.000
Min	0.611	0.611	-0.025
Average	0.980	0.857	1.042
Max	1.225	1.225	1.816
UL	25.000	25.000	25.000

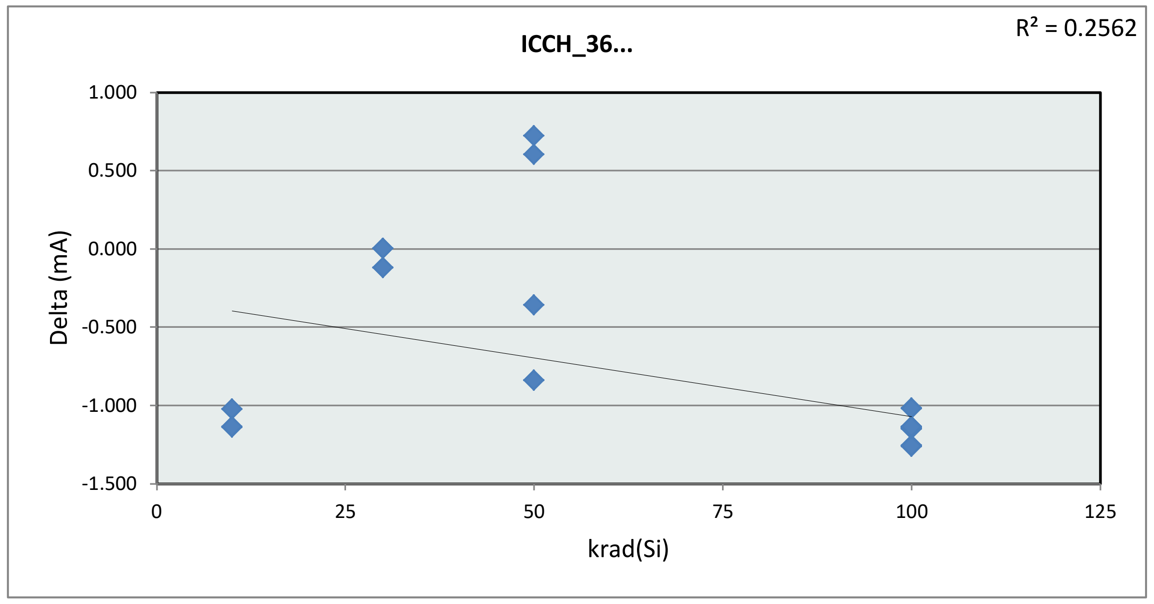


Delta Threshold	10.00%

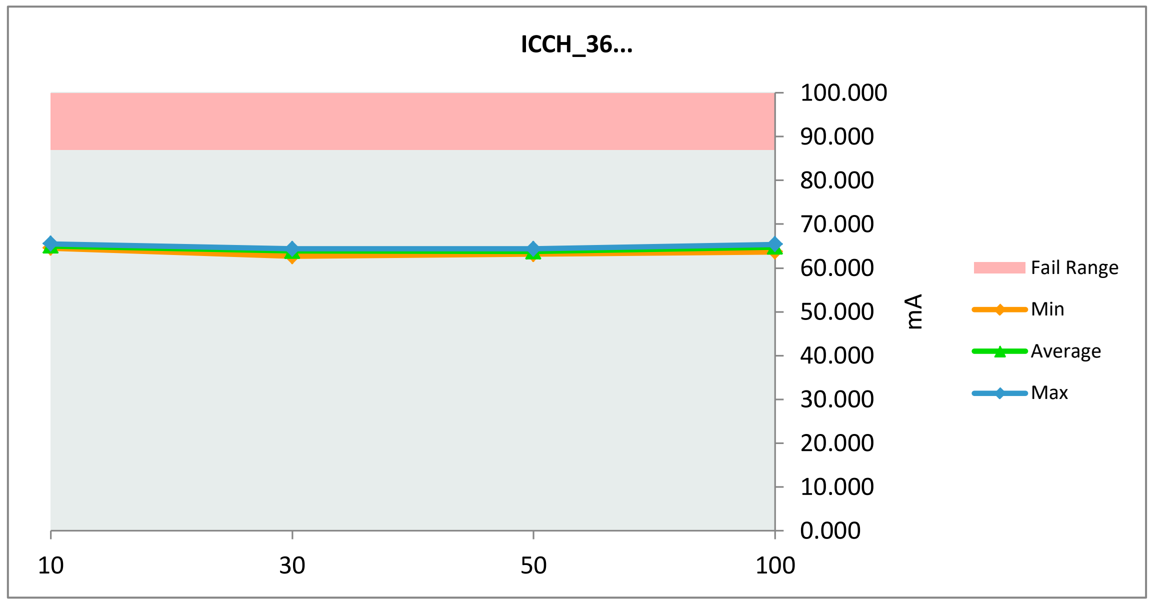
HDR Biased TID Report
SN55LVCP22A-SP

HDR Biased TID Report
SN55LVCP22A-SP

		ICCH_36...		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	87	87	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	64.237	65.373	-1.136
10	2	63.877	65.017	-1.140
10	3	63.637	64.660	-1.023
10	4	63.517	64.541	-1.024
10	5	64.357	65.492	-1.135
30	1	63.997	64.116	-0.119
30	2	62.676	62.675	0.001
30	3	64.357	64.356	0.001
30	4	64.117	64.116	0.001
30	5	63.877	63.996	-0.119
50	11	63.157	63.996	-0.839
50	12	63.877	63.155	0.722
50	13	64.357	63.756	0.601
50	14	62.556	63.395	-0.839
50	15	63.997	64.356	-0.359
100	22	63.277	64.539	-1.262
100	23	62.797	63.945	-1.148
100	24	63.277	64.421	-1.144
100	25	64.117	65.371	-1.254
100	26	63.997	65.134	-1.137
100	27	63.997	65.134	-1.137
100	28	64.117	65.253	-1.136
100	29	64.117	65.134	-1.017
100	30	63.877	65.134	-1.257
100	31	63.517	64.777	-1.260
100	32	63.277	64.421	-1.144
100	33	62.556	63.707	-1.151
100	34	63.997	65.134	-1.137
100	35	63.877	65.015	-1.138
100	36	63.997	65.134	-1.137
100	37	63.637	64.658	-1.021
100	38	63.277	64.421	-1.144
100	39	63.517	64.658	-1.141
100	41	63.397	64.539	-1.142
100	42	63.157	64.302	-1.145
100	43	63.637	64.777	-1.140
100	44	63.997	65.134	-1.137
	Max	64.357	65.492	0.722
	Average	63.676	64.534	-0.858
	Min	62.556	62.675	-1.262
	Std Dev	0.501	0.653	0.539

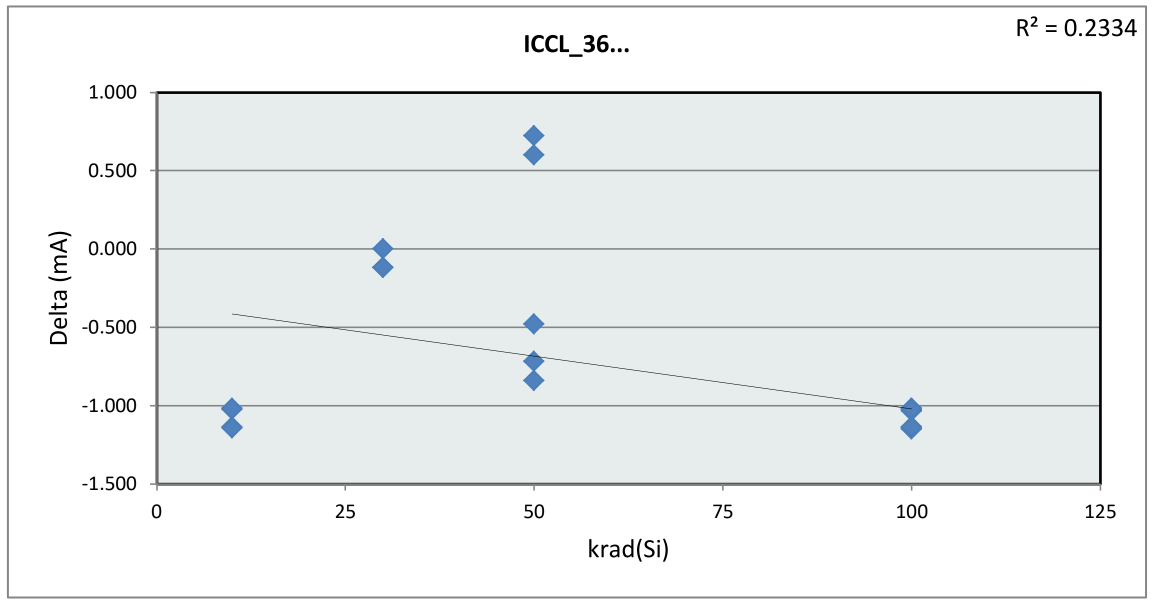


	ICCH_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	64.541	62.675	63.155	63.707
Average	65.017	63.852	63.732	64.761
Max	65.492	64.356	64.356	65.371
UL	87.000	87.000	87.000	87.000

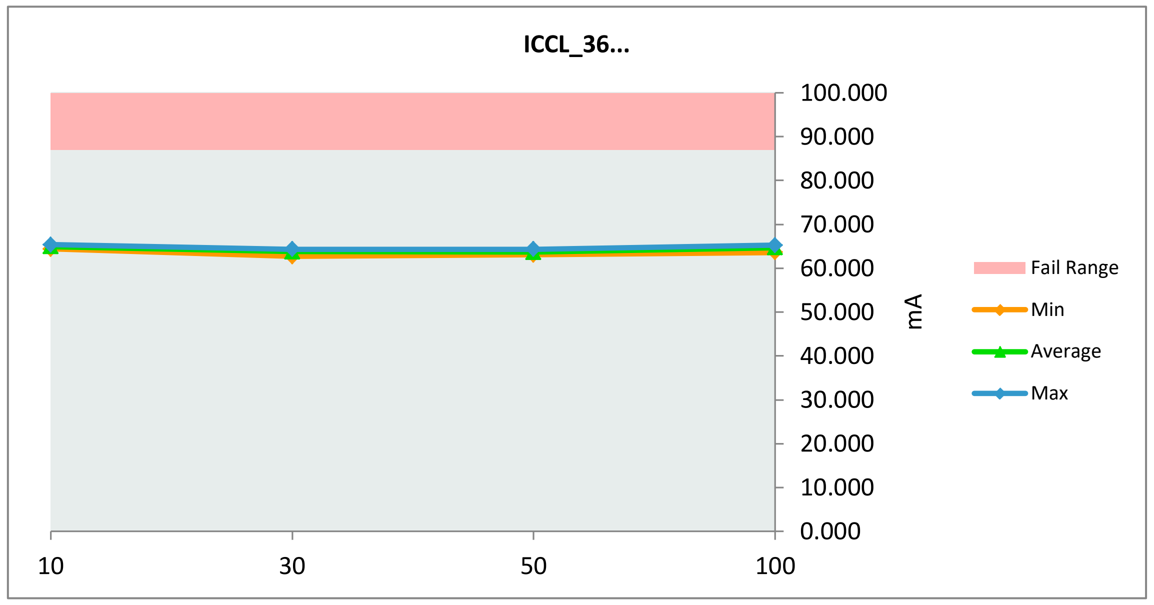


HDR Biased TID Report
SN55LVCP22A-SP

		ICCL_36...		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		87	87	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	64.237	65.373	-1.136
10	2	63.877	64.898	-1.021
10	3	63.517	64.660	-1.143
10	4	63.397	64.422	-1.025
10	5	64.357	65.373	-1.016
30	1	63.877	63.996	-0.119
30	2	62.556	62.675	-0.119
30	3	64.237	64.356	-0.119
30	4	63.997	64.116	-0.119
30	5	63.877	63.876	0.001
50	11	63.157	63.996	-0.839
50	12	63.757	63.035	0.722
50	13	64.357	63.756	0.601
50	14	62.556	63.275	-0.719
50	15	63.877	64.356	-0.479
100	22	63.277	64.421	-1.144
100	23	62.676	63.826	-1.150
100	24	63.277	64.302	-1.025
100	25	64.117	65.253	-1.136
100	26	63.997	65.015	-1.018
100	27	63.997	65.015	-1.018
100	28	64.117	65.253	-1.136
100	29	63.997	65.134	-1.137
100	30	63.877	65.015	-1.138
100	31	63.517	64.658	-1.141
100	32	63.277	64.421	-1.144
100	33	62.556	63.589	-1.033
100	34	63.997	65.134	-1.137
100	35	63.877	65.015	-1.138
100	36	63.997	65.015	-1.018
100	37	63.637	64.658	-1.021
100	38	63.277	64.302	-1.025
100	39	63.397	64.539	-1.142
100	41	63.397	64.539	-1.142
100	42	63.157	64.183	-1.026
100	43	63.517	64.658	-1.141
100	44	63.877	65.015	-1.138
	Max	64.357	65.373	0.722
	Average	63.634	64.463	-0.829
	Min	62.556	62.675	-1.150
	Std Dev	0.501	0.653	0.507



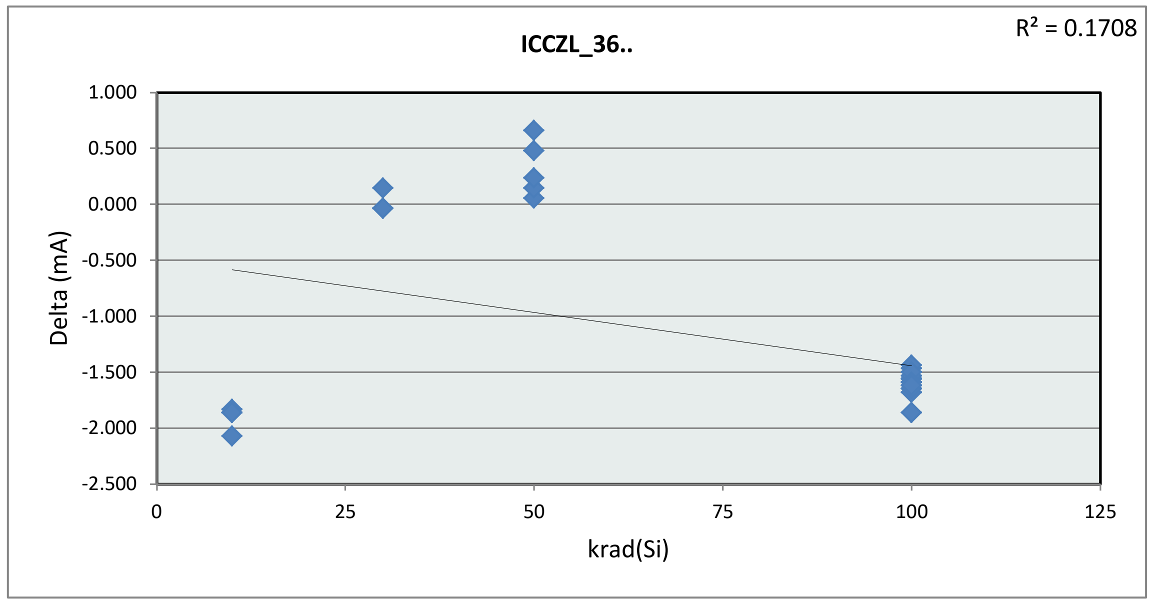
	ICCL_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	64.422	62.675	63.035	63.589
Average	64.945	63.804	63.684	64.680
Max	65.373	64.356	64.356	65.253
UL	87.000	87.000	87.000	87.000



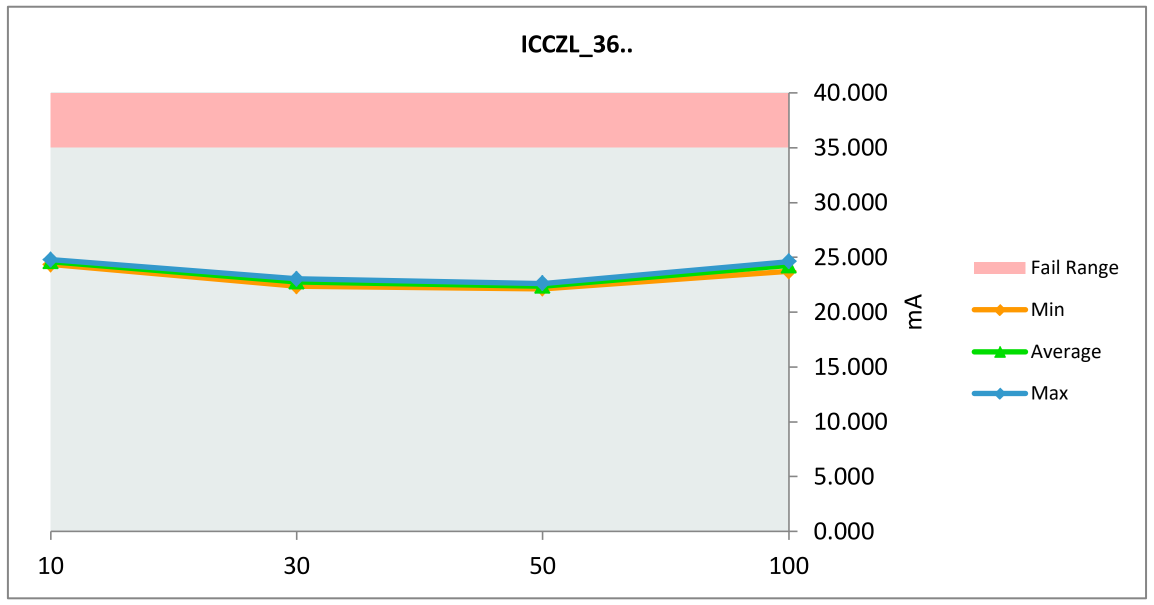
HDR Biased TID Report
SN55LVCP22A-SP

	ICCZL_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	22.677	24.750	-2.073
10	2	22.768	24.630	-1.862
10	3	22.677	24.539	-1.862
10	4	22.525	24.358	-1.833
10	5	22.920	24.781	-1.861
30	1	22.791	22.829	-0.038
30	2	22.305	22.343	-0.038
30	3	23.003	23.041	-0.038
30	4	22.912	22.950	-0.038
30	5	22.821	22.677	0.144
50	11	22.518	22.464	0.054
50	12	22.821	22.161	0.660
50	13	22.973	22.495	0.478
50	14	22.275	22.131	0.144
50	15	22.851	22.616	0.236
100	22	22.586	24.236	-1.650
100	23	22.282	23.844	-1.562
100	24	22.495	24.085	-1.590
100	25	22.829	24.296	-1.467
100	26	22.768	24.266	-1.498
100	27	22.829	24.266	-1.437
100	28	22.768	24.628	-1.860
100	29	22.768	24.628	-1.860
100	30	22.829	24.508	-1.679
100	31	22.647	24.206	-1.559
100	32	22.464	24.055	-1.591
100	33	22.191	23.723	-1.532
100	34	22.798	24.387	-1.589
100	35	22.798	24.387	-1.589
100	36	22.889	24.568	-1.679
100	37	22.707	24.206	-1.499
100	38	22.434	24.025	-1.591
100	39	22.647	24.296	-1.649
100	41	22.616	24.266	-1.650
100	42	22.495	24.115	-1.620
100	43	22.707	24.357	-1.650
100	44	22.829	24.447	-1.618
	Max	23.003	24.781	0.660
	Average	22.681	23.853	-1.172
	Min	22.191	22.131	-2.073
	Std Dev	0.205	0.836	0.838



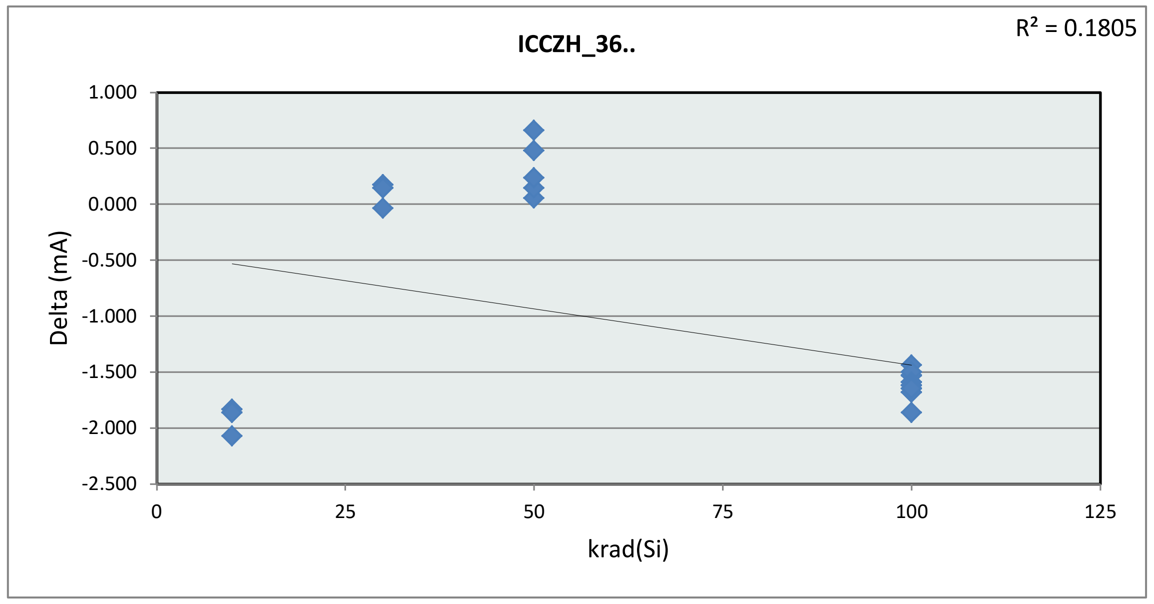
	ICCZL_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	24.358	22.343	22.131	23.723
Average	24.612	22.768	22.373	24.263
Max	24.781	23.041	22.616	24.628
UL	35.000	35.000	35.000	35.000



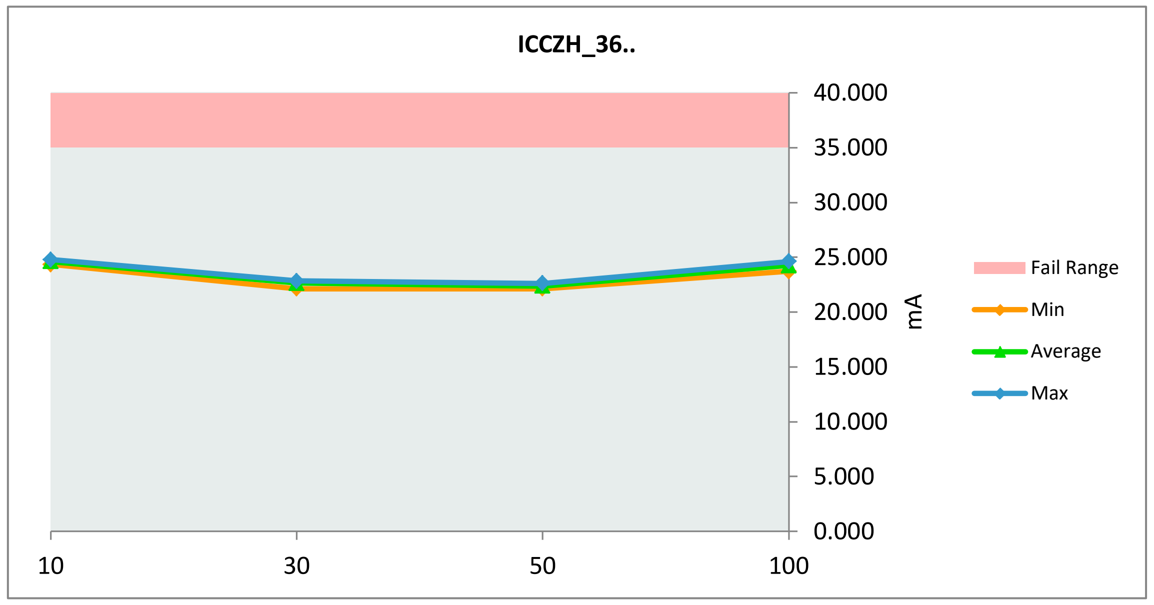
HDR Biased TID Report
SN55LVCP22A-SP

	ICCZH_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	22.677	24.750	-2.073
10	2	22.768	24.630	-1.862
10	3	22.677	24.509	-1.832
10	4	22.525	24.358	-1.833
10	5	22.920	24.781	-1.861
30	1	22.791	22.829	-0.038
30	2	22.305	22.131	0.174
30	3	23.003	22.829	0.174
30	4	22.912	22.768	0.144
30	5	22.821	22.677	0.144
50	11	22.518	22.464	0.054
50	12	22.821	22.161	0.660
50	13	22.973	22.495	0.478
50	14	22.275	22.131	0.144
50	15	22.851	22.616	0.236
100	22	22.586	24.236	-1.650
100	23	22.313	23.844	-1.531
100	24	22.495	24.085	-1.590
100	25	22.798	24.296	-1.498
100	26	22.768	24.266	-1.498
100	27	22.829	24.266	-1.437
100	28	22.768	24.387	-1.619
100	29	22.768	24.628	-1.860
100	30	22.829	24.508	-1.679
100	31	22.647	24.236	-1.589
100	32	22.464	24.085	-1.621
100	33	22.191	23.723	-1.532
100	34	22.798	24.387	-1.589
100	35	22.798	24.417	-1.619
100	36	22.889	24.568	-1.679
100	37	22.707	24.206	-1.499
100	38	22.434	24.025	-1.591
100	39	22.616	24.296	-1.680
100	41	22.616	24.266	-1.650
100	42	22.495	24.115	-1.620
100	43	22.707	24.357	-1.650
100	44	22.798	24.447	-1.649
	Max	23.003	24.781	0.660
	Average	22.680	23.832	-1.152
	Min	22.191	22.131	-2.073
	Std Dev	0.203	0.854	0.859



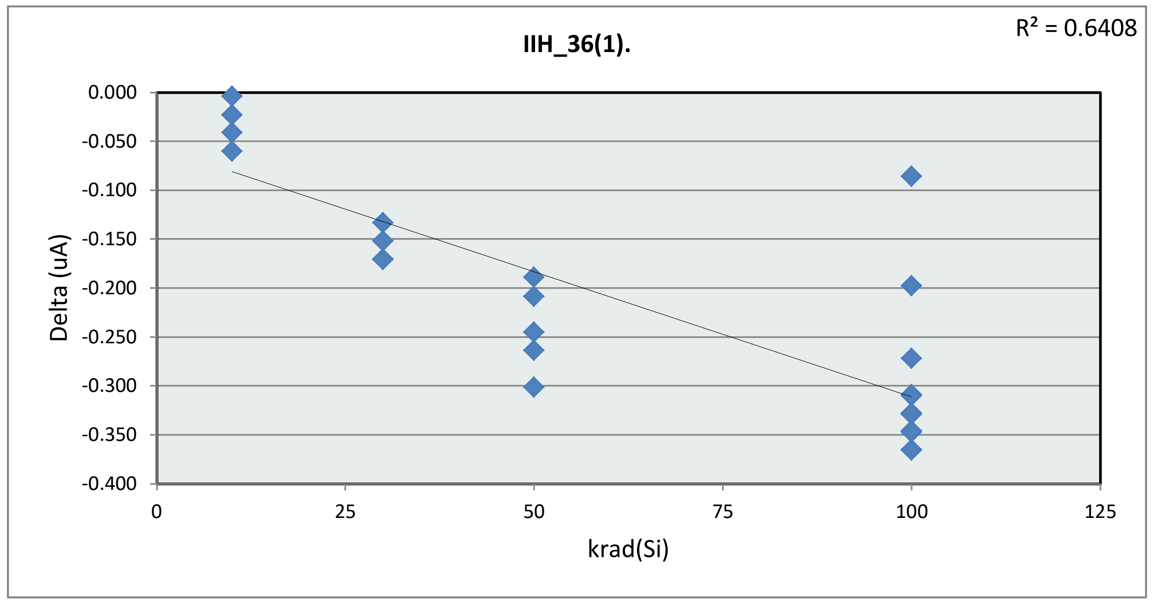
	ICCZH_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	24.358	22.131	22.131	23.723
Average	24.606	22.647	22.373	24.257
Max	24.781	22.829	22.616	24.628
UL	35.000	35.000	35.000	35.000



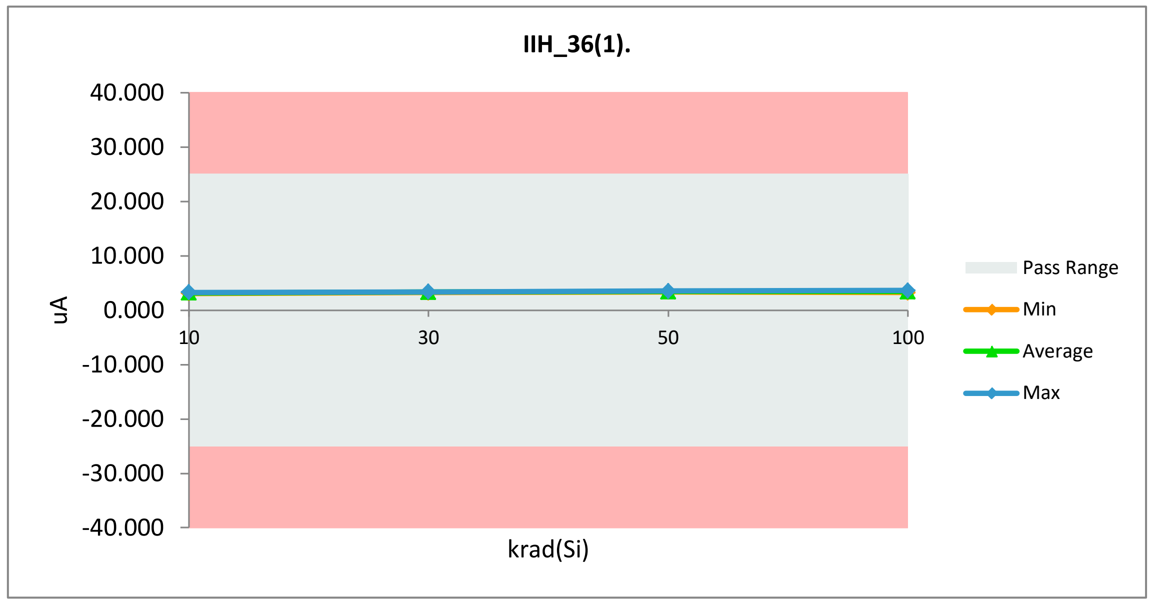
HDR Biased TID Report
SN55LVCP22A-SP

	IIH_36(1).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	3.099	3.159	-0.060
10	2	3.155	3.196	-0.041
10	3	3.080	3.103	-0.023
10	4	3.285	3.289	-0.004
10	5	3.136	3.159	-0.023
30	1	3.162	3.314	-0.152
30	2	3.237	3.407	-0.170
30	3	3.162	3.333	-0.171
30	4	3.106	3.258	-0.152
30	5	3.125	3.258	-0.133
50	11	3.237	3.445	-0.208
50	12	3.143	3.445	-0.302
50	13	3.181	3.370	-0.189
50	14	3.274	3.519	-0.245
50	15	3.143	3.407	-0.264
100	22	3.155	3.520	-0.365
100	23	3.229	3.576	-0.347
100	24	3.211	3.557	-0.346
100	25	3.080	3.408	-0.328
100	26	3.155	3.464	-0.309
100	27	3.099	3.371	-0.272
100	28	3.099	3.297	-0.198
100	29	3.155	3.241	-0.086
100	30	3.024	3.390	-0.366
100	31	3.136	3.483	-0.347
100	32	3.211	3.557	-0.346
100	33	3.285	3.613	-0.328
100	34	3.099	3.427	-0.328
100	35	3.062	3.408	-0.346
100	36	3.117	3.446	-0.329
100	37	3.099	3.408	-0.309
100	38	3.341	3.427	-0.086
100	39	3.099	3.446	-0.347
100	41	3.043	3.390	-0.347
100	42	3.155	3.483	-0.328
100	43	3.080	3.390	-0.310
100	44	3.099	3.427	-0.328
	Max	3.341	3.613	-0.004
	Average	3.150	3.389	-0.239
	Min	3.024	3.103	-0.366
	Std Dev	0.073	0.121	0.117



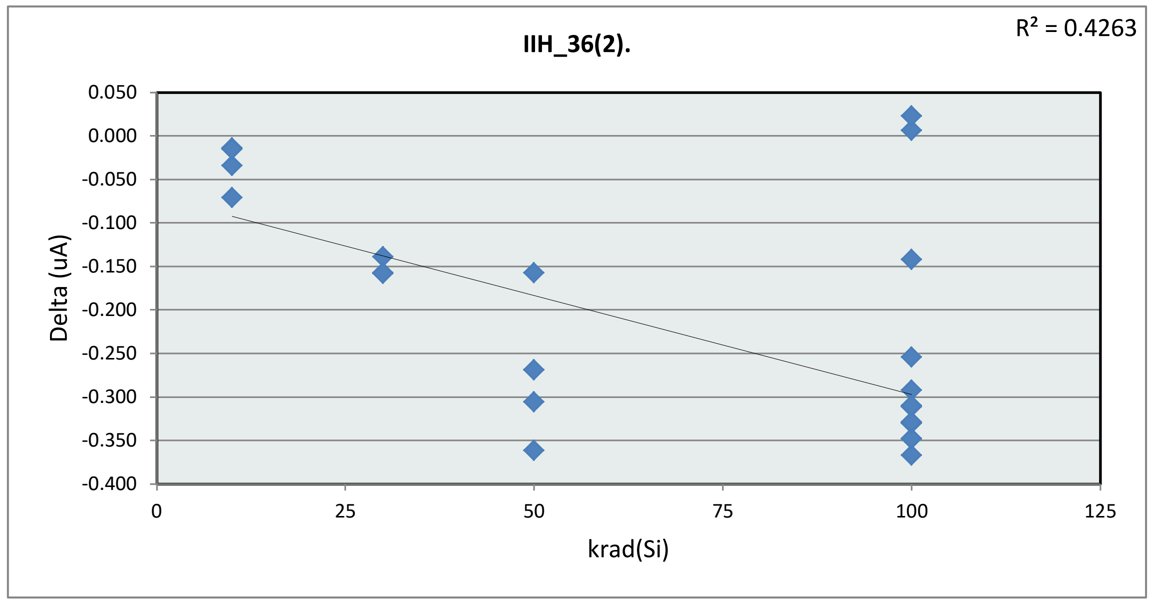
	IIH_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.103	3.258	3.370	3.241
Average	3.181	3.314	3.437	3.442
Max	3.289	3.407	3.519	3.613
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
SN55LVCP22A-SP

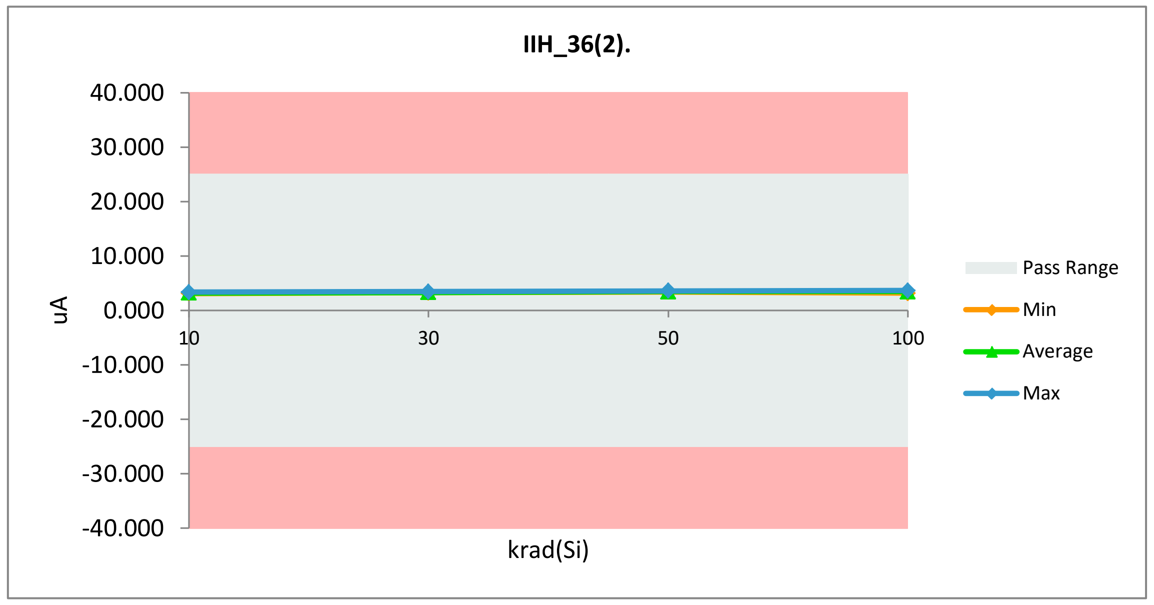
	IIH_36(2).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	3.127	3.198	-0.071
10	2	3.201	3.235	-0.034
10	3	3.127	3.142	-0.015
10	4	3.369	3.383	-0.014
10	5	3.183	3.198	-0.015
30	1	3.182	3.321	-0.139
30	2	3.312	3.470	-0.158
30	3	3.163	3.321	-0.158
30	4	3.107	3.265	-0.158
30	5	3.126	3.284	-0.158
50	11	3.275	3.432	-0.157
50	12	3.163	3.525	-0.362
50	13	3.163	3.432	-0.269
50	14	3.349	3.618	-0.269
50	15	3.126	3.432	-0.306
100	22	3.220	3.568	-0.348
100	23	3.294	3.624	-0.330
100	24	3.276	3.606	-0.330
100	25	3.127	3.438	-0.311
100	26	3.220	3.512	-0.292
100	27	3.109	3.363	-0.254
100	28	3.109	3.251	-0.142
100	29	3.183	3.177	0.006
100	30	3.071	3.438	-0.367
100	31	3.164	3.512	-0.348
100	32	3.276	3.624	-0.348
100	33	3.369	3.680	-0.311
100	34	3.146	3.475	-0.329
100	35	3.090	3.419	-0.329
100	36	3.090	3.438	-0.348
100	37	3.127	3.438	-0.311
100	38	3.424	3.401	0.023
100	39	3.146	3.494	-0.348
100	41	3.090	3.419	-0.329
100	42	3.201	3.531	-0.330
100	43	3.090	3.419	-0.329
100	44	3.146	3.456	-0.310
	Max	3.424	3.680	0.023
	Average	3.188	3.420	-0.232
	Min	3.071	3.142	-0.367
	Std Dev	0.091	0.136	0.127



	IIH_36(2).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

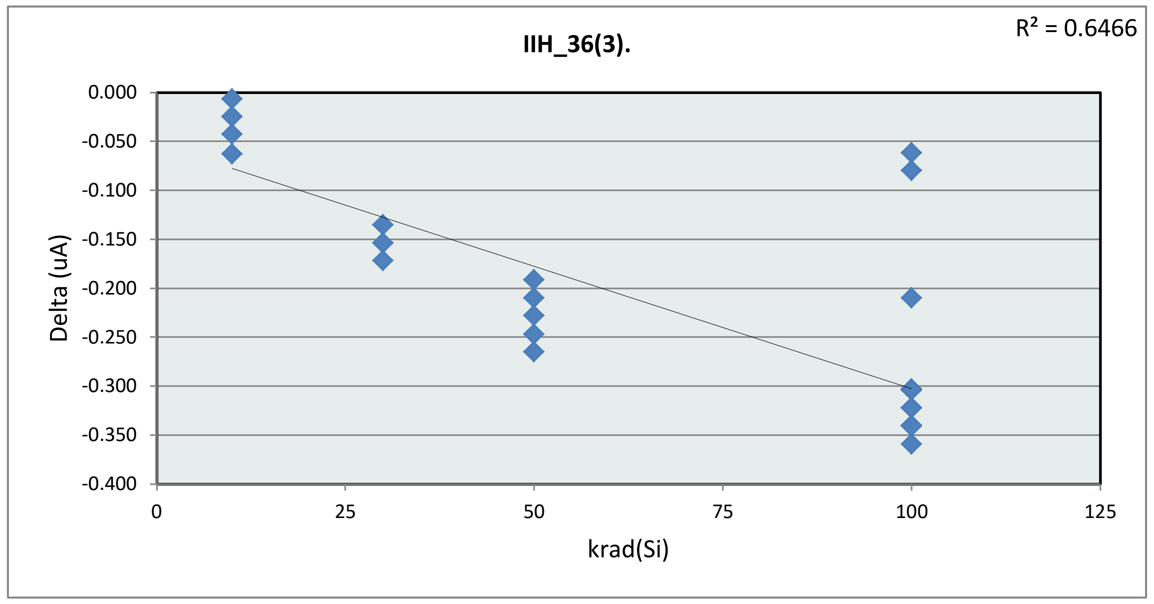
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.142	3.265	3.432	3.177
Average	3.231	3.332	3.488	3.467
Max	3.383	3.470	3.618	3.680
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
SN55LVCP22A-SP

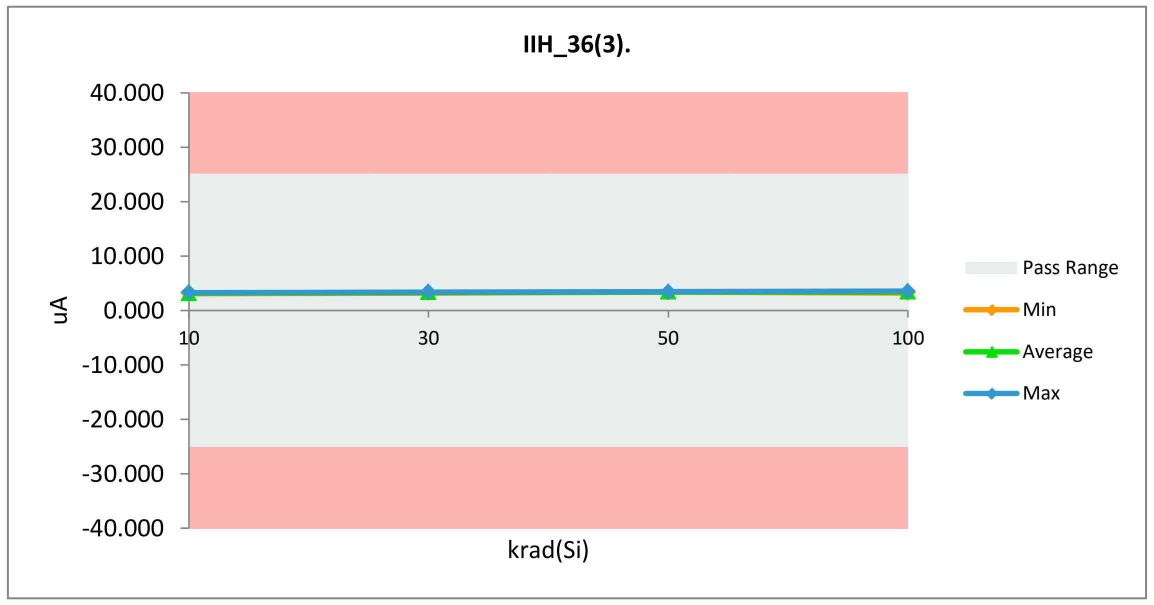
	IIH_36(3).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	3.103	3.166	-0.063
10	2	3.178	3.203	-0.025
10	3	3.085	3.128	-0.043
10	4	3.308	3.315	-0.007
10	5	3.159	3.184	-0.025
30	1	3.181	3.335	-0.154
30	2	3.237	3.409	-0.172
30	3	3.181	3.335	-0.154
30	4	3.107	3.242	-0.135
30	5	3.107	3.242	-0.135
50	11	3.237	3.447	-0.210
50	12	3.181	3.428	-0.247
50	13	3.200	3.391	-0.191
50	14	3.274	3.502	-0.228
50	15	3.144	3.409	-0.265
100	22	3.159	3.518	-0.359
100	23	3.234	3.574	-0.340
100	24	3.215	3.556	-0.341
100	25	3.103	3.407	-0.304
100	26	3.178	3.481	-0.303
100	27	3.085	3.388	-0.303
100	28	3.122	3.332	-0.210
100	29	3.178	3.258	-0.080
100	30	3.047	3.388	-0.341
100	31	3.159	3.500	-0.341
100	32	3.215	3.556	-0.341
100	33	3.271	3.593	-0.322
100	34	3.122	3.425	-0.303
100	35	3.085	3.407	-0.322
100	36	3.122	3.444	-0.322
100	37	3.103	3.425	-0.322
100	38	3.345	3.407	-0.062
100	39	3.122	3.462	-0.340
100	41	3.066	3.407	-0.341
100	42	3.178	3.500	-0.322
100	43	3.085	3.388	-0.303
100	44	3.122	3.425	-0.303
	Max	3.345	3.593	-0.007
	Average	3.162	3.394	-0.232
	Min	3.047	3.128	-0.359
	Std Dev	0.070	0.116	0.113



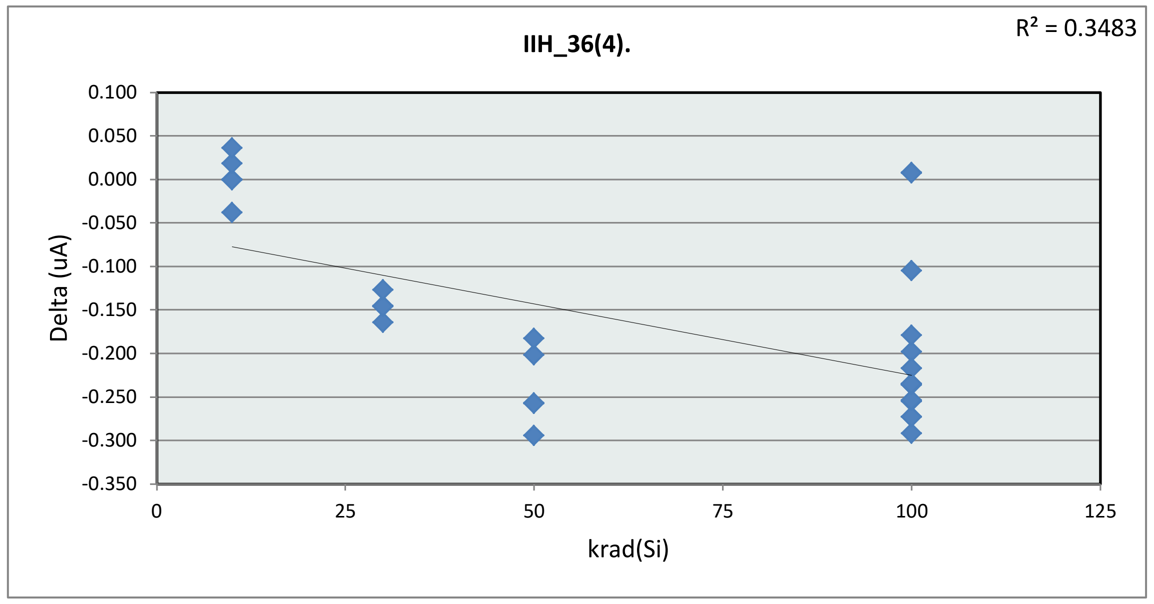
	IIH_36(3).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.128	3.242	3.391	3.258
Average	3.199	3.313	3.435	3.447
Max	3.315	3.409	3.502	3.593
UL	25.000	25.000	25.000	25.000

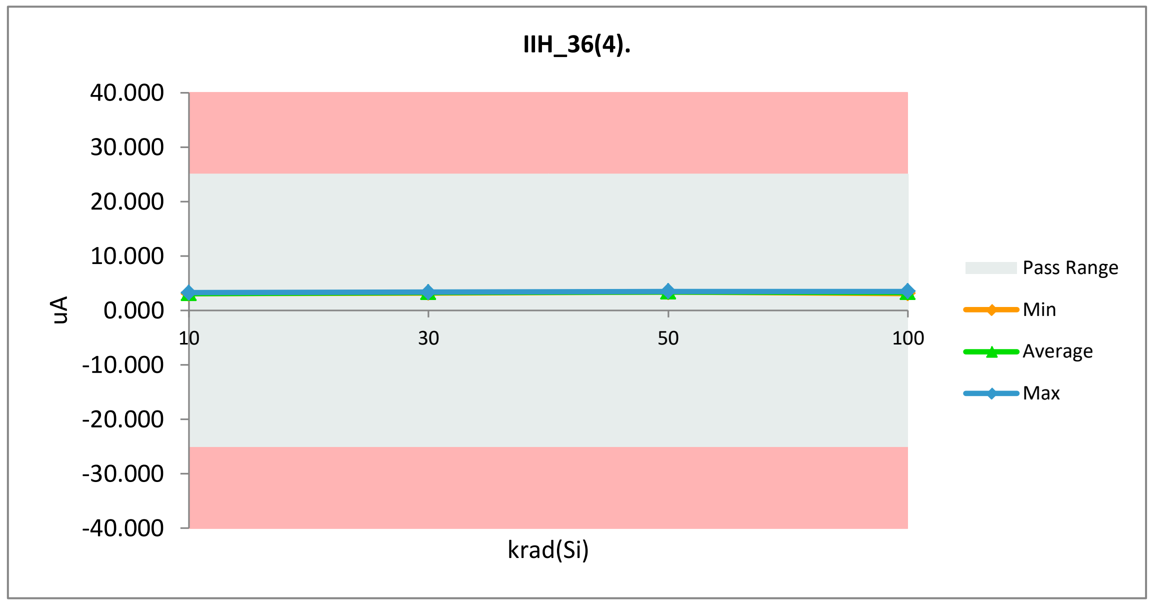


HDR Biased TID Report
SN55LVCP22A-SP

		IIH_36(4).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	3.097	3.135	-0.038
10	2	3.153	3.153	0.000
10	3	3.078	3.079	-0.001
10	4	3.302	3.284	0.018
10	5	3.171	3.135	0.036
30	1	3.185	3.331	-0.146
30	2	3.241	3.387	-0.146
30	3	3.167	3.331	-0.164
30	4	3.111	3.257	-0.146
30	5	3.111	3.238	-0.127
50	11	3.241	3.443	-0.202
50	12	3.167	3.461	-0.294
50	13	3.185	3.368	-0.183
50	14	3.260	3.517	-0.257
50	15	3.148	3.406	-0.258
100	22	3.153	3.426	-0.273
100	23	3.227	3.482	-0.255
100	24	3.209	3.445	-0.236
100	25	3.097	3.314	-0.217
100	26	3.190	3.388	-0.198
100	27	3.097	3.276	-0.179
100	28	3.097	3.202	-0.105
100	29	3.153	3.145	0.008
100	30	3.041	3.314	-0.273
100	31	3.134	3.426	-0.292
100	32	3.190	3.463	-0.273
100	33	3.283	3.519	-0.236
100	34	3.097	3.332	-0.235
100	35	3.060	3.314	-0.254
100	36	3.134	3.351	-0.217
100	37	3.097	3.332	-0.235
100	38	3.339	3.332	0.007
100	39	3.097	3.370	-0.273
100	41	3.060	3.314	-0.254
100	42	3.171	3.407	-0.236
100	43	3.078	3.314	-0.236
100	44	3.097	3.332	-0.235
	Max	3.339	3.519	0.036
	Average	3.155	3.333	-0.179
	Min	3.041	3.079	-0.294
	Std Dev	0.072	0.110	0.101



	IIH_36(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.079	3.238	3.368	3.145
Average	3.157	3.309	3.439	3.354
Max	3.284	3.387	3.517	3.519
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
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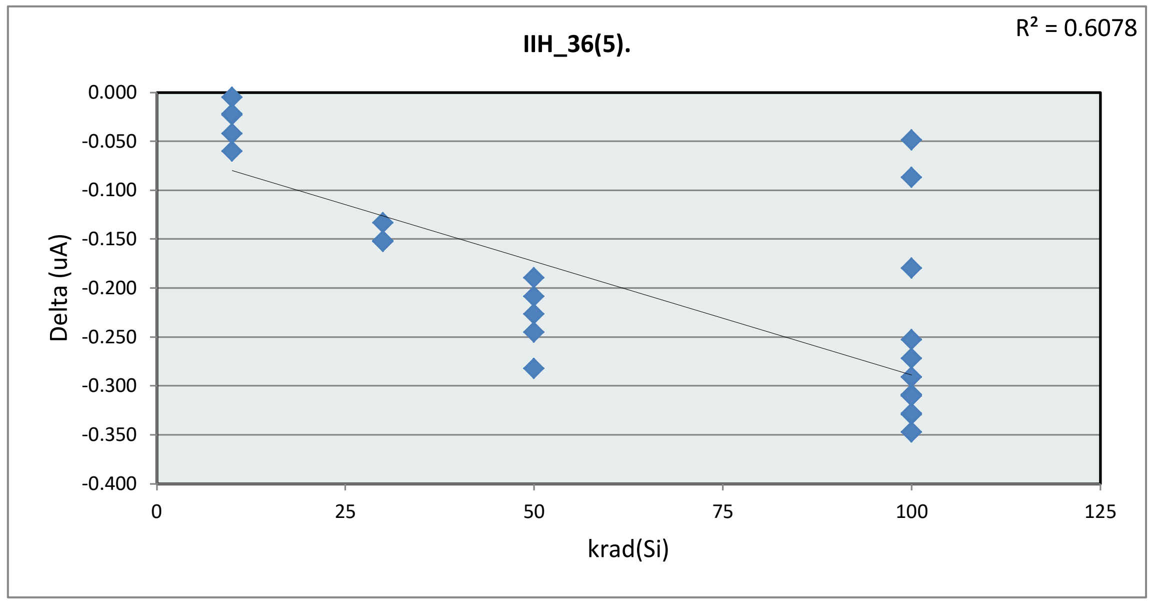
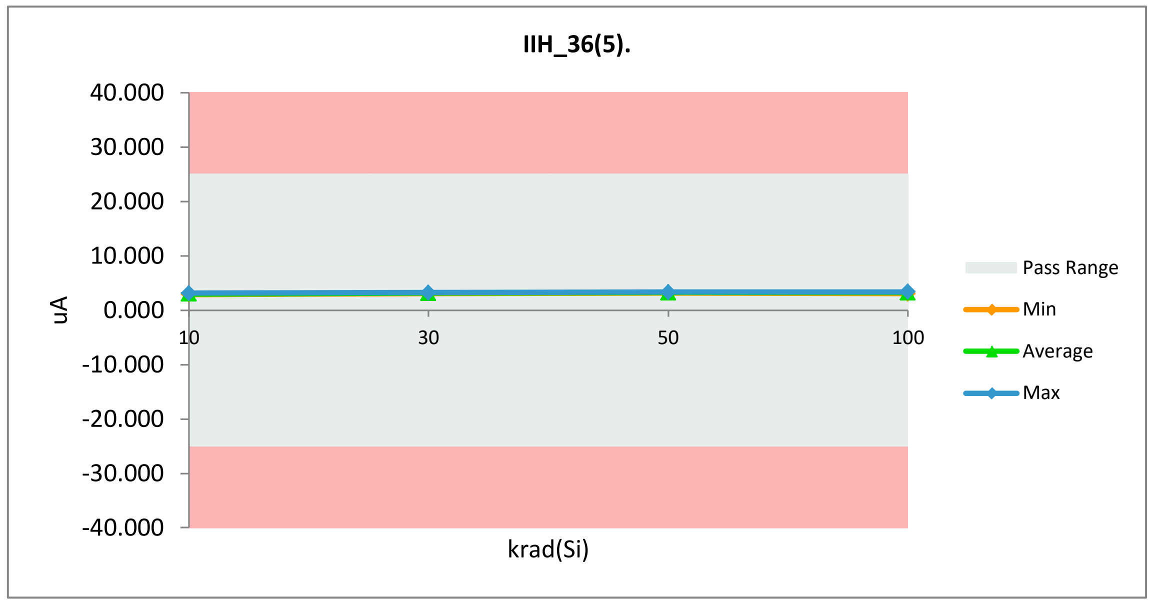
	IIH_36(5).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	2.913	2.973	-0.060
10	2	2.968	3.010	-0.042
10	3	2.894	2.917	-0.023
10	4	3.099	3.121	-0.022
10	5	2.968	2.973	-0.005
30	1	2.994	3.147	-0.153
30	2	3.069	3.221	-0.152
30	3	2.994	3.147	-0.153
30	4	2.920	3.072	-0.152
30	5	2.939	3.072	-0.133
50	11	3.050	3.240	-0.190
50	12	2.976	3.258	-0.282
50	13	2.994	3.203	-0.209
50	14	3.088	3.314	-0.226
50	15	2.976	3.221	-0.245
100	22	2.968	3.315	-0.347
100	23	3.062	3.371	-0.309
100	24	3.024	3.353	-0.329
100	25	2.913	3.204	-0.291
100	26	2.987	3.259	-0.272
100	27	2.913	3.166	-0.253
100	28	2.931	3.111	-0.180
100	29	2.968	3.055	-0.087
100	30	2.875	3.204	-0.329
100	31	2.950	3.297	-0.347
100	32	3.043	3.353	-0.310
100	33	3.099	3.408	-0.309
100	34	2.931	3.259	-0.328
100	35	2.894	3.204	-0.310
100	36	2.931	3.241	-0.310
100	37	2.913	3.222	-0.309
100	38	3.173	3.222	-0.049
100	39	2.931	3.241	-0.310
100	41	2.875	3.185	-0.310
100	42	2.987	3.297	-0.310
100	43	2.894	3.204	-0.310
100	44	2.931	3.222	-0.291
	Max	3.173	3.408	-0.005
	Average	2.974	3.197	-0.223
	Min	2.875	2.917	-0.347
	Std Dev	0.071	0.115	0.108



	IIH_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.917	3.072	3.203	3.055
Average	2.999	3.132	3.247	3.245
Max	3.121	3.221	3.314	3.408
UL	25.000	25.000	25.000	25.000



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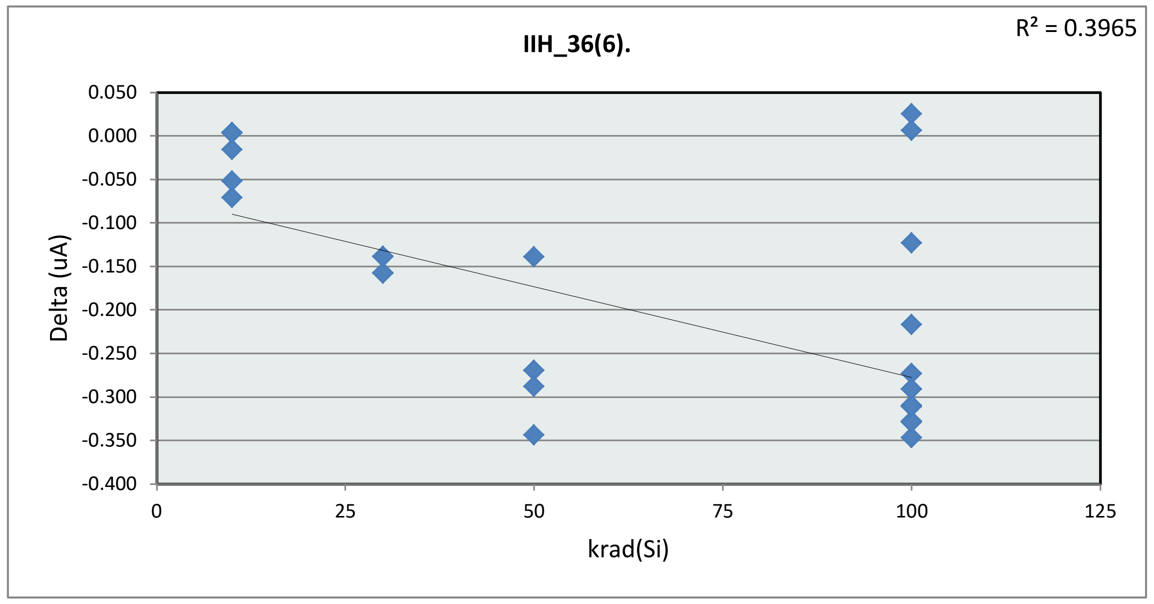
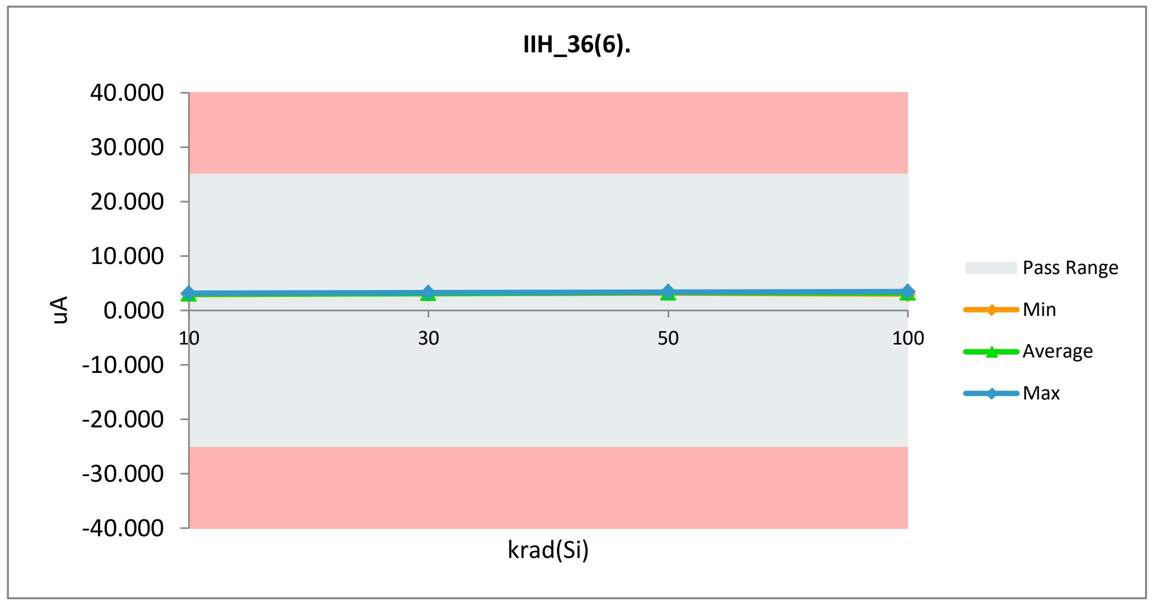
		IIH_36(6).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	2.923	2.994	-0.071
10	2	2.997	3.049	-0.052
10	3	2.941	2.957	-0.016
10	4	3.183	3.179	0.004
10	5	2.997	2.994	0.003
30	1	2.977	3.116	-0.139
30	2	3.126	3.284	-0.158
30	3	2.959	3.116	-0.157
30	4	2.922	3.079	-0.157
30	5	2.940	3.079	-0.139
50	11	3.089	3.228	-0.139
50	12	2.977	3.321	-0.344
50	13	2.977	3.247	-0.270
50	14	3.145	3.414	-0.269
50	15	2.940	3.228	-0.288
100	22	3.016	3.363	-0.347
100	23	3.109	3.438	-0.329
100	24	3.071	3.382	-0.311
100	25	2.923	3.214	-0.291
100	26	3.016	3.289	-0.273
100	27	2.923	3.140	-0.217
100	28	2.923	3.046	-0.123
100	29	2.978	2.972	0.006
100	30	2.886	3.214	-0.328
100	31	2.960	3.307	-0.347
100	32	3.090	3.419	-0.329
100	33	3.183	3.456	-0.273
100	34	2.960	3.251	-0.291
100	35	2.904	3.214	-0.310
100	36	2.904	3.214	-0.310
100	37	2.923	3.214	-0.291
100	38	3.220	3.195	0.025
100	39	2.960	3.289	-0.329
100	41	2.904	3.214	-0.310
100	42	3.016	3.326	-0.310
100	43	2.904	3.214	-0.310
100	44	2.960	3.251	-0.291
	Max	3.220	3.456	0.025
	Average	2.995	3.214	-0.218
	Min	2.886	2.957	-0.347
	Std Dev	0.090	0.133	0.120



	IIH_36(6).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.957	3.079	3.228	2.972
Average	3.035	3.135	3.288	3.256
Max	3.179	3.284	3.414	3.456
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
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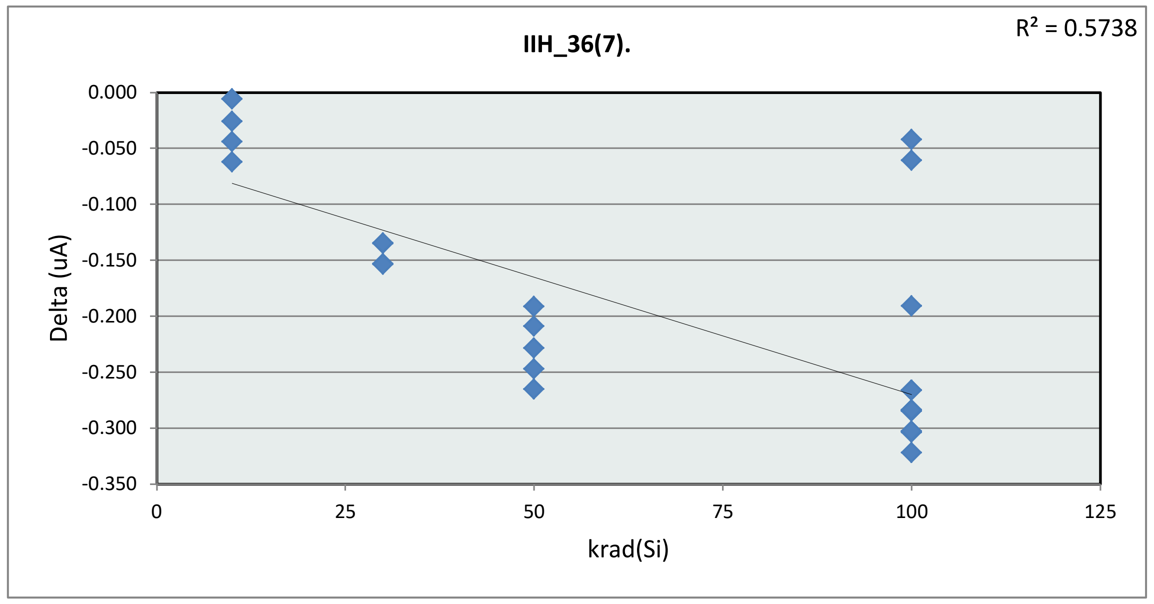
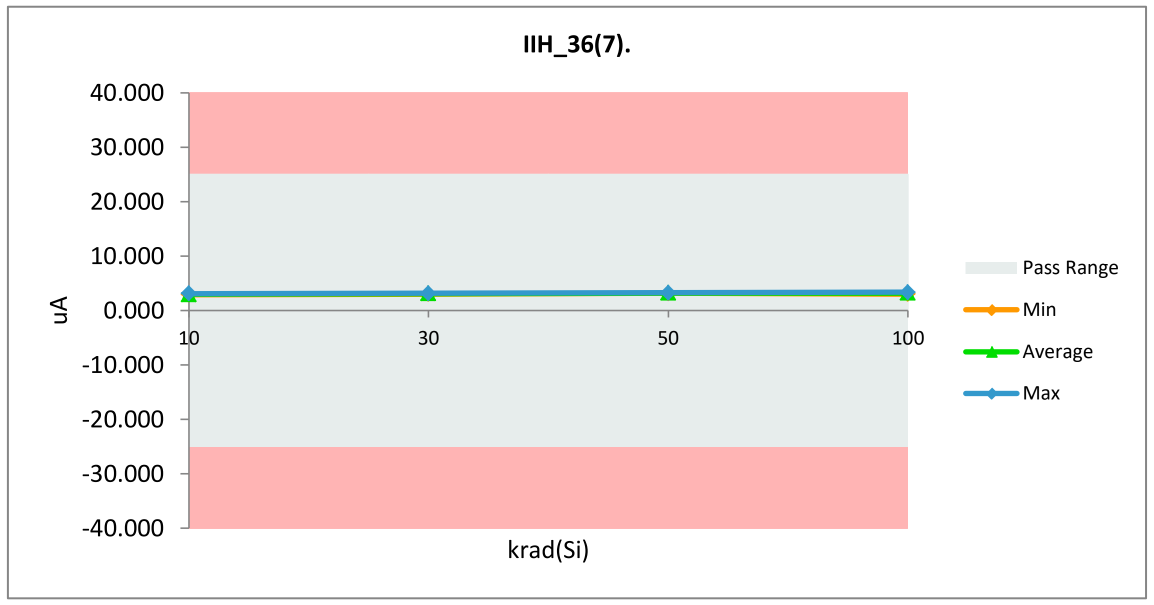
		IIH_36(7).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	2.917	2.979	-0.062
10	2	2.973	3.017	-0.044
10	3	2.898	2.924	-0.026
10	4	3.122	3.128	-0.006
10	5	2.973	2.979	-0.006
30	1	2.995	3.148	-0.153
30	2	3.051	3.204	-0.153
30	3	2.995	3.130	-0.135
30	4	2.920	3.055	-0.135
30	5	2.920	3.074	-0.154
50	11	3.051	3.242	-0.191
50	12	2.995	3.242	-0.247
50	13	2.995	3.204	-0.209
50	14	3.069	3.298	-0.229
50	15	2.958	3.223	-0.265
100	22	2.992	3.295	-0.303
100	23	3.047	3.351	-0.304
100	24	3.029	3.332	-0.303
100	25	2.917	3.183	-0.266
100	26	2.992	3.258	-0.266
100	27	2.898	3.164	-0.266
100	28	2.936	3.127	-0.191
100	29	2.973	3.034	-0.061
100	30	2.880	3.183	-0.303
100	31	2.954	3.276	-0.322
100	32	3.029	3.332	-0.303
100	33	3.085	3.369	-0.284
100	34	2.936	3.220	-0.284
100	35	2.898	3.183	-0.285
100	36	2.936	3.220	-0.284
100	37	2.936	3.202	-0.266
100	38	3.141	3.183	-0.042
100	39	2.936	3.239	-0.303
100	41	2.898	3.183	-0.285
100	42	2.992	3.276	-0.284
100	43	2.898	3.183	-0.285
100	44	2.936	3.220	-0.284
	Max	3.141	3.369	-0.006
	Average	2.975	3.185	-0.211
	Min	2.880	2.924	-0.322
	Std Dev	0.066	0.107	0.101



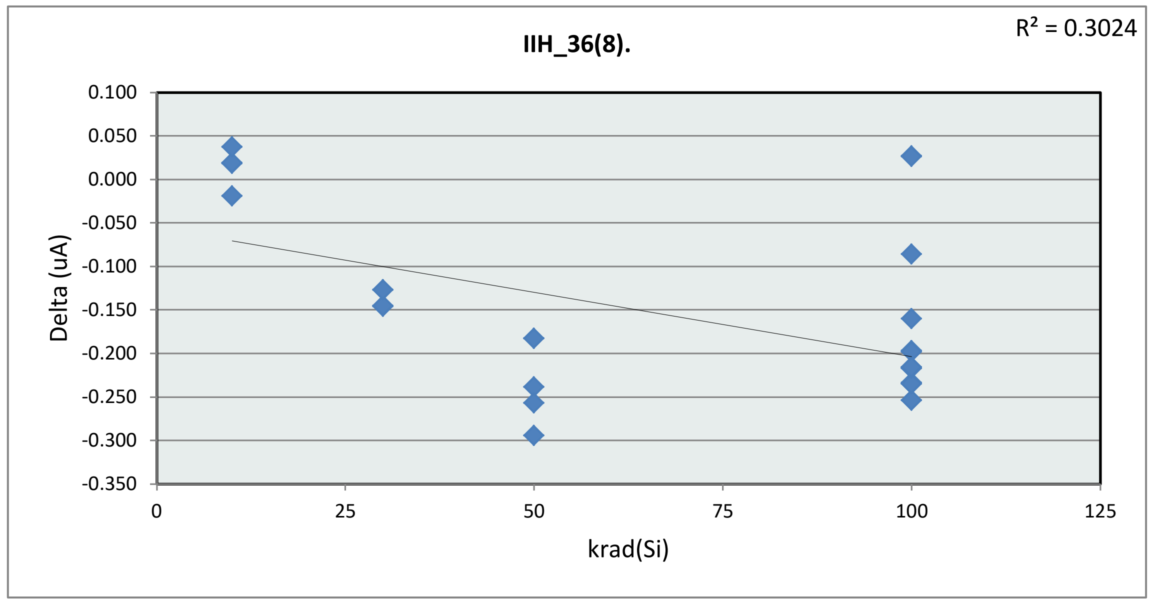
	IIH_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.924	3.055	3.204	3.034
Average	3.005	3.122	3.242	3.228
Max	3.128	3.204	3.298	3.369
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
SN55LVCP22A-SP

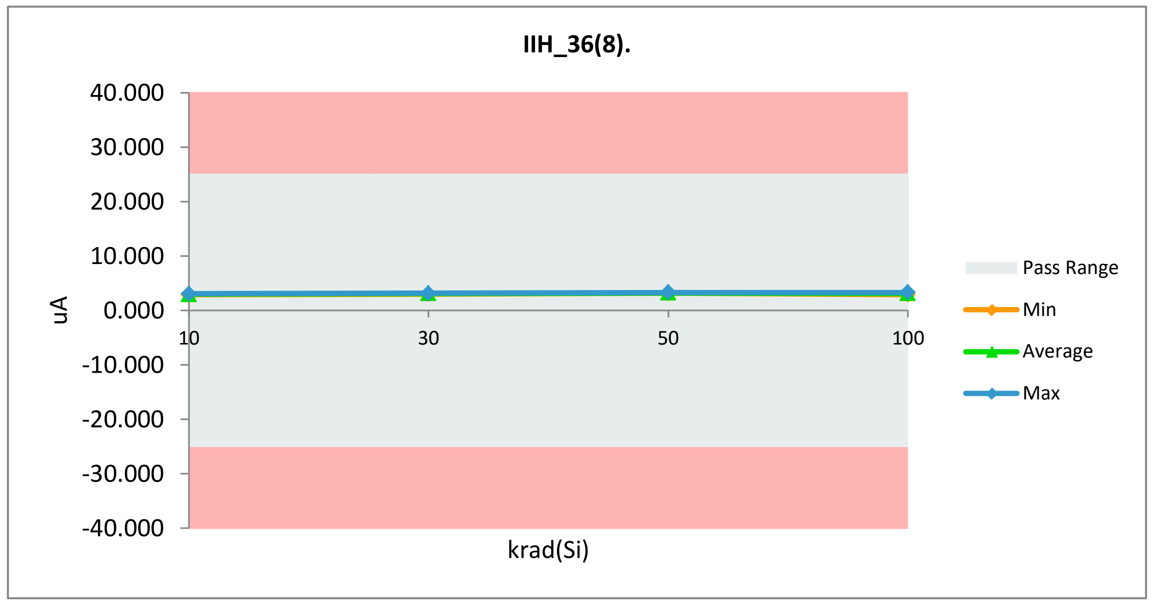
	IIH_36(8).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	2.929	2.948	-0.019
10	2	2.985	2.967	0.018
10	3	2.911	2.892	0.019
10	4	3.116	3.097	0.019
10	5	2.985	2.948	0.037
30	1	2.999	3.126	-0.127
30	2	3.055	3.201	-0.146
30	3	2.981	3.126	-0.145
30	4	2.925	3.070	-0.145
30	5	2.925	3.052	-0.127
50	11	3.055	3.238	-0.183
50	12	2.981	3.275	-0.294
50	13	2.999	3.182	-0.183
50	14	3.074	3.312	-0.238
50	15	2.962	3.219	-0.257
100	22	2.985	3.220	-0.235
100	23	3.041	3.276	-0.235
100	24	3.022	3.239	-0.217
100	25	2.911	3.108	-0.197
100	26	2.985	3.183	-0.198
100	27	2.911	3.071	-0.160
100	28	2.929	3.015	-0.086
100	29	2.967	2.940	0.027
100	30	2.873	3.108	-0.235
100	31	2.948	3.202	-0.254
100	32	3.004	3.258	-0.254
100	33	3.097	3.314	-0.217
100	34	2.911	3.145	-0.234
100	35	2.892	3.108	-0.216
100	36	2.929	3.145	-0.216
100	37	2.929	3.127	-0.198
100	38	3.153	3.127	0.026
100	39	2.929	3.164	-0.235
100	41	2.873	3.108	-0.235
100	42	2.985	3.202	-0.217
100	43	2.873	3.089	-0.216
100	44	2.911	3.127	-0.216
	Max	3.153	3.314	0.037
	Average	2.971	3.133	-0.162
	Min	2.873	2.892	-0.294
	Std Dev	0.069	0.106	0.098



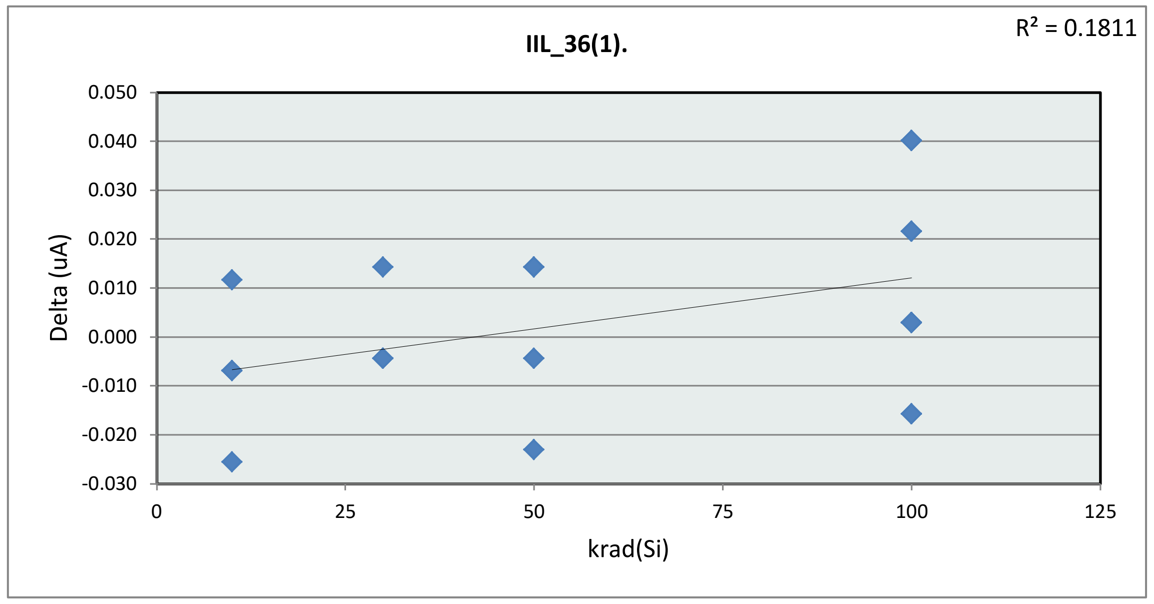
	IIH_36(8).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.892	3.052	3.182	2.940
Average	2.970	3.115	3.245	3.149
Max	3.097	3.201	3.312	3.314
UL	25.000	25.000	25.000	25.000

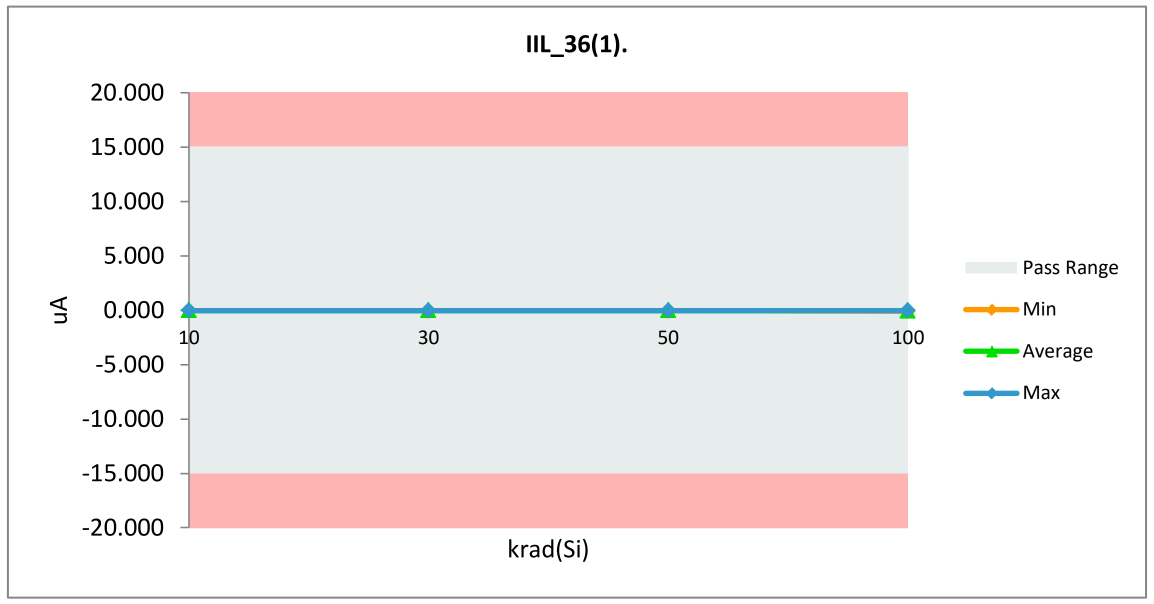


HDR Biased TID Report
SN55LVCP22A-SP

		IIL_36(1).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.031	-0.024	-0.007
10	2	-0.031	-0.024	-0.007
10	3	-0.012	-0.024	0.012
10	4	-0.031	-0.024	-0.007
10	5	-0.049	-0.024	-0.026
30	1	-0.023	-0.019	-0.004
30	2	-0.023	-0.019	-0.004
30	3	-0.023	-0.019	-0.004
30	4	-0.023	-0.019	-0.004
30	5	-0.023	-0.037	0.014
50	11	-0.023	-0.019	-0.004
50	12	-0.042	-0.019	-0.023
50	13	-0.023	-0.019	-0.004
50	14	-0.023	-0.037	0.014
50	15	-0.023	-0.037	0.014
100	22	-0.031	-0.034	0.003
100	23	-0.049	-0.034	-0.016
100	24	-0.012	-0.034	0.022
100	25	-0.012	-0.052	0.040
100	26	-0.031	-0.034	0.003
100	27	-0.031	-0.034	0.003
100	28	-0.031	-0.015	-0.016
100	29	-0.012	-0.034	0.022
100	30	-0.031	-0.034	0.003
100	31	-0.031	-0.034	0.003
100	32	-0.049	-0.090	0.040
100	33	-0.031	-0.034	0.003
100	34	-0.031	-0.034	0.003
100	35	-0.031	-0.052	0.022
100	36	-0.031	-0.071	0.040
100	37	-0.031	-0.034	0.003
100	38	-0.031	-0.015	-0.016
100	39	-0.031	-0.052	0.022
100	41	-0.012	-0.052	0.040
100	42	-0.012	-0.052	0.040
100	43	-0.031	-0.034	0.003
100	44	-0.031	-0.034	0.003
	Max	-0.012	-0.015	0.040
	Average	-0.028	-0.034	0.006
	Min	-0.049	-0.090	-0.026
	Std Dev	0.010	0.016	0.018



	IIL_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.024	-0.037	-0.037	-0.090
Average	-0.024	-0.022	-0.026	-0.041
Max	-0.024	-0.019	-0.019	-0.015
UL	15.000	15.000	15.000	15.000



HDR Biased TID Report
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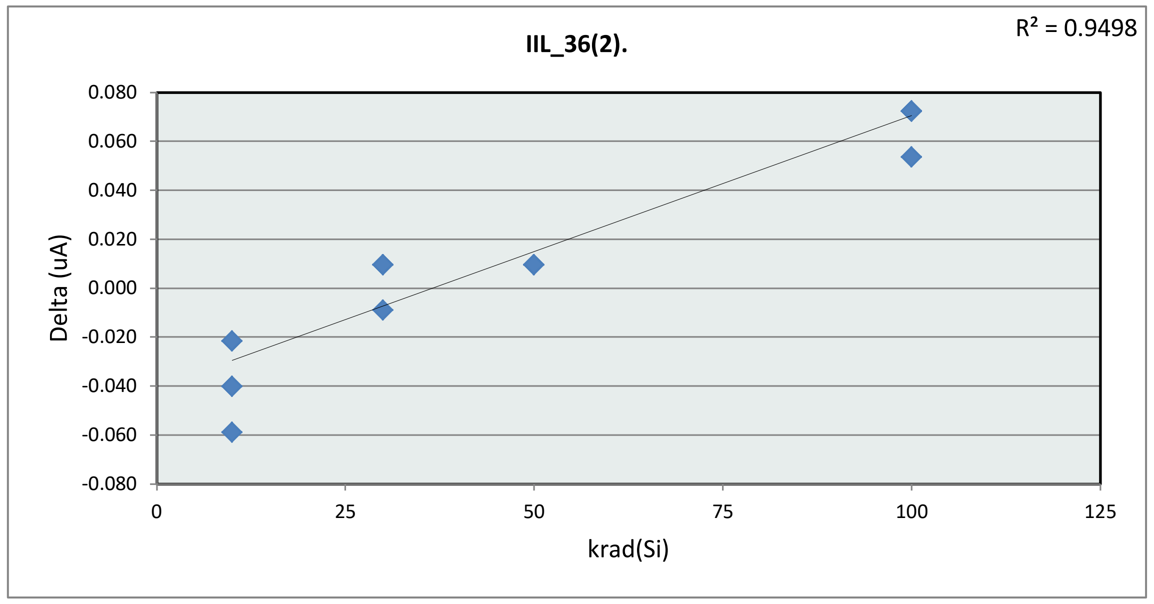
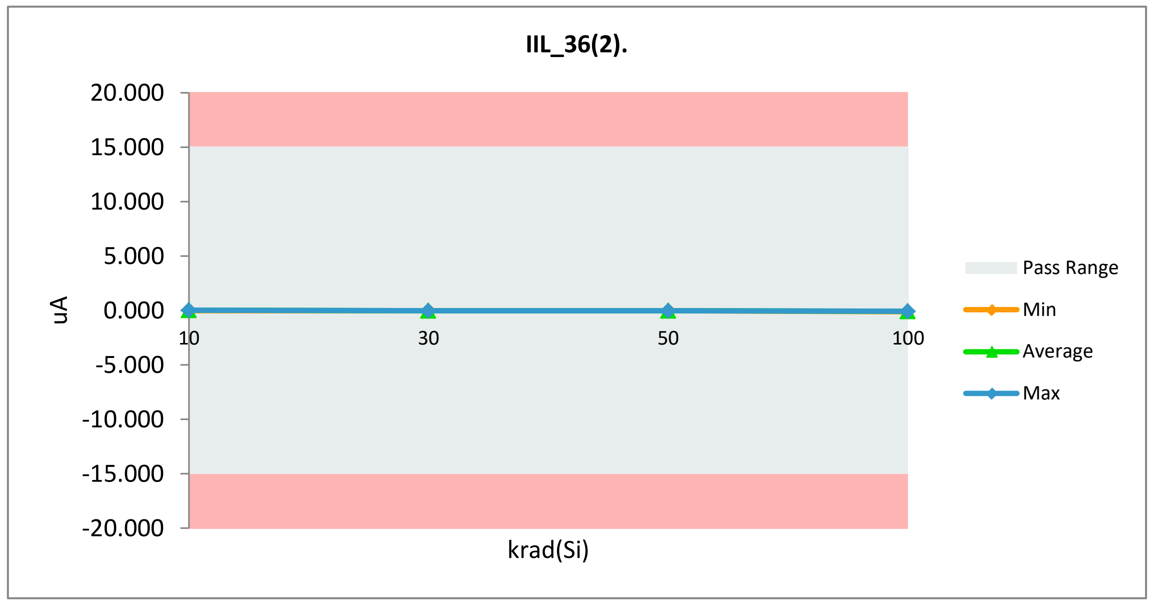
	IIL_36(2).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.014	0.027	-0.040
10	2	-0.014	0.027	-0.040
10	3	-0.014	0.008	-0.022
10	4	-0.014	0.008	-0.022
10	5	-0.032	0.027	-0.059
30	1	-0.016	-0.025	0.009
30	2	-0.016	-0.025	0.009
30	3	-0.016	-0.025	0.009
30	4	-0.034	-0.025	-0.009
30	5	-0.016	-0.025	0.009
50	11	-0.016	-0.025	0.009
50	12	-0.016	-0.025	0.009
50	13	-0.016	-0.025	0.009
50	14	-0.016	-0.025	0.009
50	15	-0.016	-0.025	0.009
100	22	-0.014	-0.086	0.072
100	23	-0.014	-0.086	0.072
100	24	-0.014	-0.086	0.072
100	25	-0.014	-0.086	0.072
100	26	-0.014	-0.086	0.072
100	27	-0.014	-0.086	0.072
100	28	-0.014	-0.086	0.072
100	29	-0.032	-0.086	0.054
100	30	-0.014	-0.086	0.072
100	31	-0.014	-0.086	0.072
100	32	-0.014	-0.086	0.072
100	33	-0.014	-0.067	0.054
100	34	-0.014	-0.086	0.072
100	35	-0.014	-0.086	0.072
100	36	-0.014	-0.086	0.072
100	37	-0.014	-0.086	0.072
100	38	-0.014	-0.086	0.072
100	39	-0.014	-0.086	0.072
100	41	-0.014	-0.086	0.072
100	42	-0.014	-0.086	0.072
100	43	-0.014	-0.086	0.072
100	44	-0.014	-0.086	0.072
	Max	-0.014	0.027	0.072
	Average	-0.016	-0.055	0.039
	Min	-0.034	-0.086	-0.059
	Std Dev	0.005	0.040	0.042

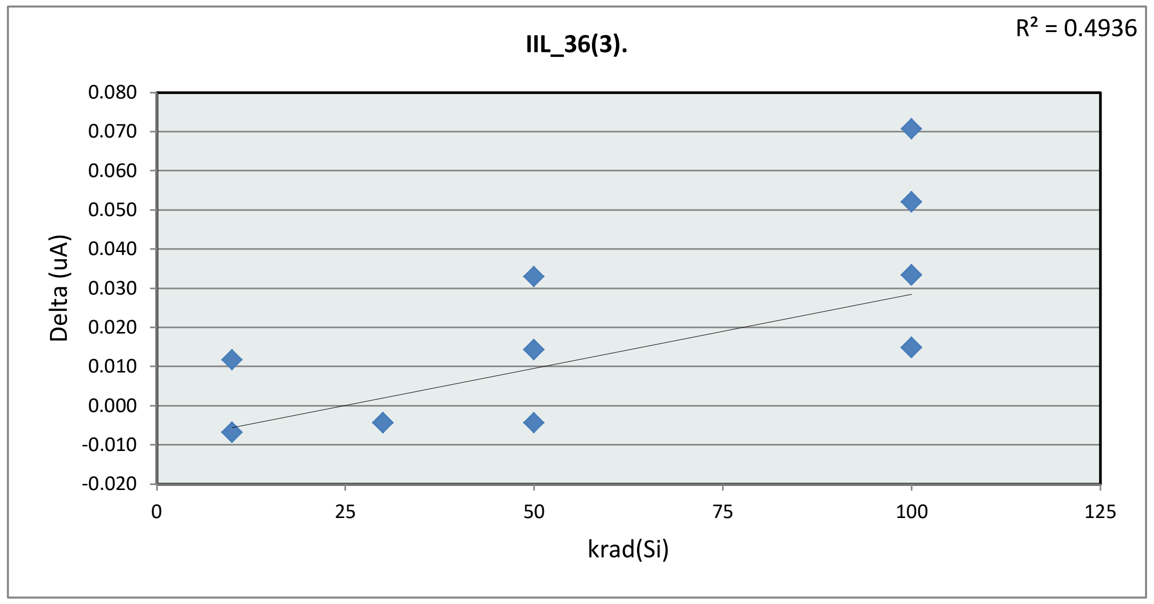


	IIL_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	0.008	-0.025	-0.025	-0.086
Average	0.019	-0.025	-0.025	-0.085
Max	0.027	-0.025	-0.025	-0.067
UL	15.000	15.000	15.000	15.000

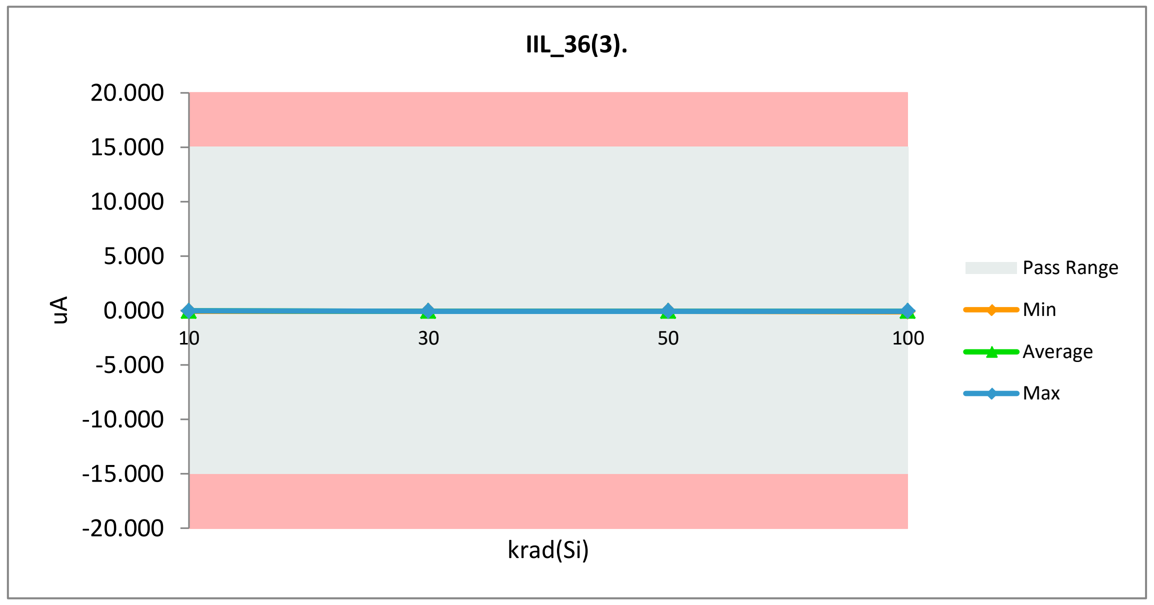


HDR Biased TID Report
SN55LVCP22A-SP

		IIL_36(3).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		-15	-15	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.025	-0.018	-0.007
10	2	-0.025	-0.037	0.012
10	3	-0.025	-0.018	-0.007
10	4	-0.025	-0.018	-0.007
10	5	-0.025	-0.018	-0.007
30	1	-0.041	-0.037	-0.004
30	2	-0.041	-0.037	-0.004
30	3	-0.041	-0.037	-0.004
30	4	-0.041	-0.037	-0.004
30	5	-0.041	-0.037	-0.004
50	11	-0.041	-0.055	0.014
50	12	-0.041	-0.037	-0.004
50	13	-0.023	-0.037	0.014
50	14	-0.023	-0.055	0.033
50	15	-0.023	-0.037	0.014
100	22	-0.025	-0.059	0.033
100	23	-0.025	-0.096	0.071
100	24	-0.025	-0.077	0.052
100	25	-0.025	-0.059	0.033
100	26	-0.025	-0.059	0.033
100	27	-0.025	-0.040	0.015
100	28	-0.025	-0.040	0.015
100	29	-0.025	-0.040	0.015
100	30	-0.025	-0.040	0.015
100	31	-0.025	-0.059	0.033
100	32	-0.044	-0.059	0.015
100	33	-0.025	-0.040	0.015
100	34	-0.025	-0.059	0.033
100	35	-0.025	-0.059	0.033
100	36	-0.025	-0.077	0.052
100	37	-0.025	-0.040	0.015
100	38	-0.025	-0.040	0.015
100	39	-0.044	-0.059	0.015
100	41	-0.025	-0.040	0.015
100	42	-0.025	-0.059	0.033
100	43	-0.025	-0.077	0.052
100	44	-0.025	-0.040	0.015
	Max	-0.023	-0.018	0.071
	Average	-0.029	-0.047	0.018
	Min	-0.044	-0.096	-0.007
	Std Dev	0.007	0.018	0.020



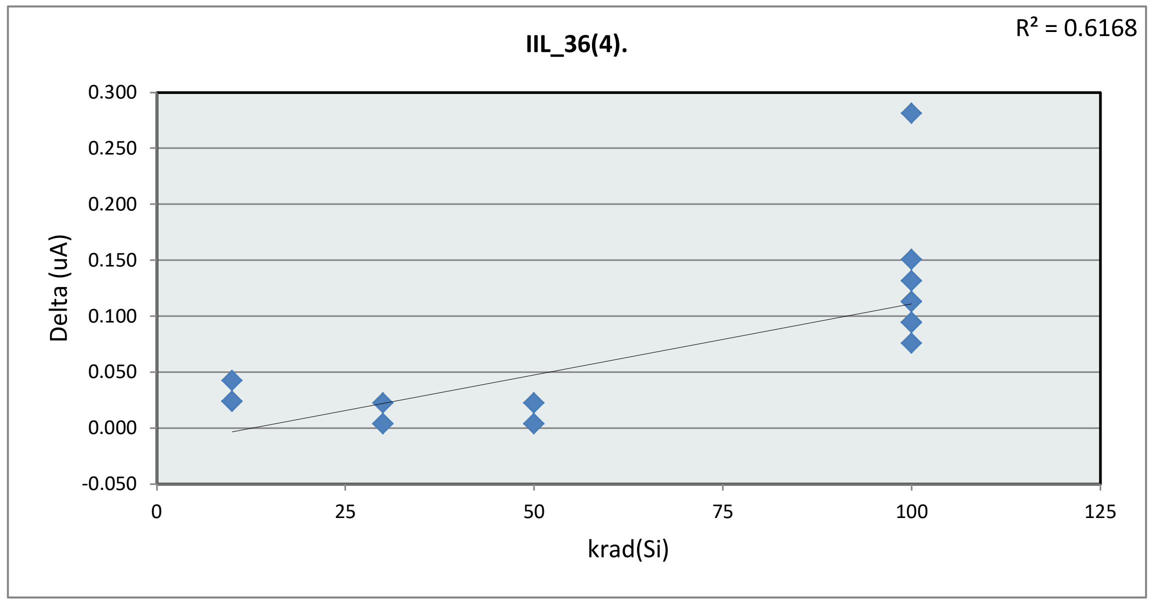
	IIL_36(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.037	-0.037	-0.055	-0.096
Average	-0.022	-0.037	-0.044	-0.055
Max	-0.018	-0.037	-0.037	-0.040
UL	15.000	15.000	15.000	15.000



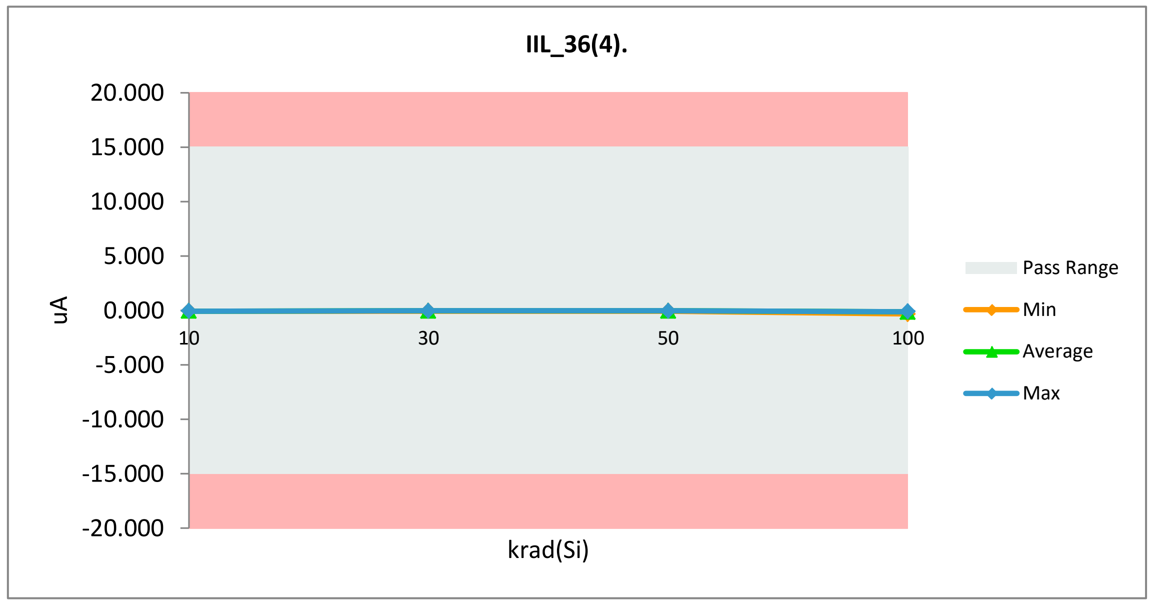
HDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(4).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.013	-0.036	0.024
10	2	-0.013	-0.036	0.024
10	3	-0.013	-0.055	0.042
10	4	-0.013	-0.036	0.024
10	5	-0.013	-0.036	0.024
30	1	-0.017	-0.021	0.004
30	2	-0.017	-0.040	0.023
30	3	-0.017	-0.021	0.004
30	4	-0.017	-0.021	0.004
30	5	-0.017	-0.021	0.004
50	11	-0.036	-0.040	0.004
50	12	-0.017	-0.021	0.004
50	13	-0.017	-0.040	0.023
50	14	-0.017	-0.021	0.004
50	15	-0.017	-0.040	0.023
100	22	-0.013	-0.107	0.094
100	23	-0.013	-0.144	0.132
100	24	-0.031	-0.126	0.094
100	25	-0.013	-0.107	0.094
100	26	-0.013	-0.107	0.094
100	27	-0.013	-0.107	0.094
100	28	-0.013	-0.107	0.094
100	29	-0.013	-0.088	0.076
100	30	-0.013	-0.126	0.113
100	31	-0.013	-0.144	0.132
100	32	-0.013	-0.126	0.113
100	33	-0.013	-0.126	0.113
100	34	-0.013	-0.126	0.113
100	35	-0.013	-0.126	0.113
100	36	-0.013	-0.163	0.150
100	37	-0.031	-0.144	0.113
100	38	-0.013	-0.107	0.094
100	39	-0.031	-0.313	0.281
100	41	-0.013	-0.126	0.113
100	42	-0.013	-0.126	0.113
100	43	-0.013	-0.126	0.113
100	44	-0.013	-0.107	0.094
	Max	-0.013	-0.021	0.281
	Average	-0.016	-0.091	0.075
	Min	-0.036	-0.313	0.004
	Std Dev	0.006	0.060	0.059



	IIL_36(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.055	-0.040	-0.040	-0.313
Average	-0.040	-0.025	-0.033	-0.131
Max	-0.036	-0.021	-0.021	-0.088
UL	15.000	15.000	15.000	15.000



HDR Biased TID Report
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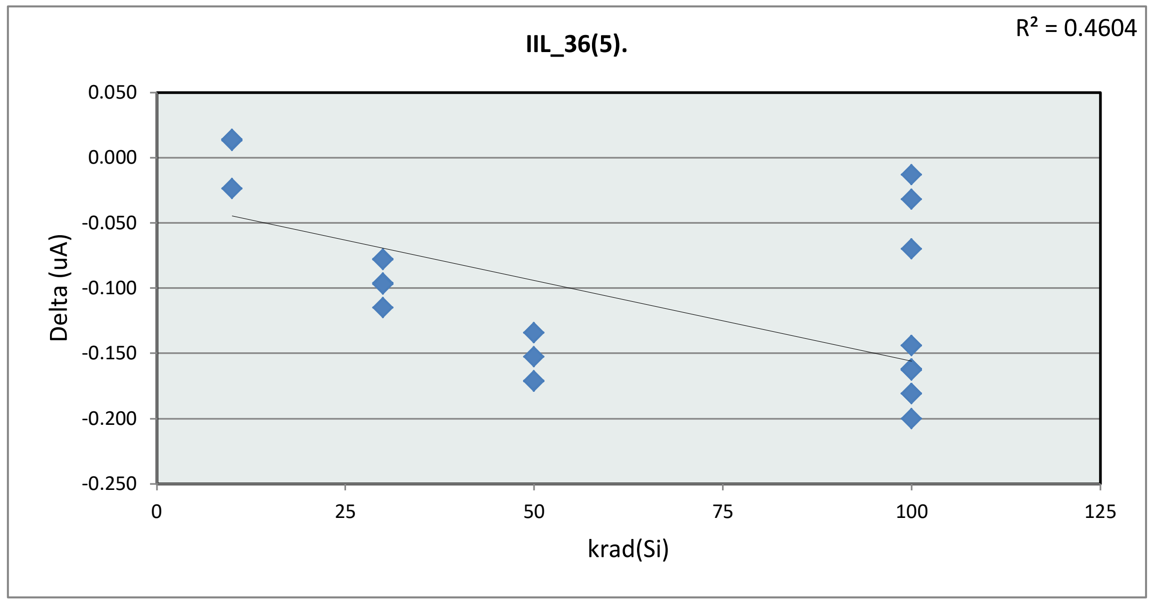
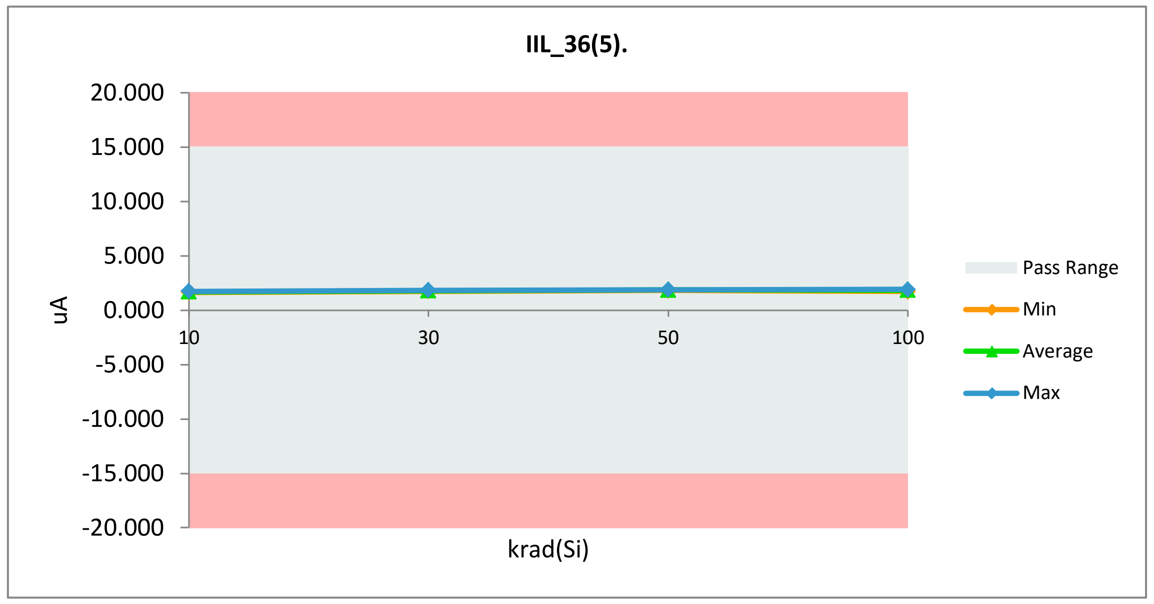
	IIL_36(5).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.646	1.670	-0.024
10	2	1.702	1.688	0.014
10	3	1.664	1.651	0.013
10	4	1.758	1.744	0.014
10	5	1.702	1.688	0.014
30	1	1.709	1.787	-0.078
30	2	1.728	1.843	-0.115
30	3	1.691	1.787	-0.096
30	4	1.672	1.750	-0.078
30	5	1.672	1.769	-0.097
50	11	1.728	1.862	-0.134
50	12	1.691	1.862	-0.171
50	13	1.691	1.825	-0.134
50	14	1.746	1.899	-0.153
50	15	1.672	1.843	-0.171
100	22	1.683	1.883	-0.200
100	23	1.739	1.901	-0.162
100	24	1.720	1.883	-0.163
100	25	1.646	1.808	-0.162
100	26	1.683	1.845	-0.162
100	27	1.646	1.790	-0.144
100	28	1.664	1.734	-0.070
100	29	1.683	1.715	-0.032
100	30	1.627	1.808	-0.181
100	31	1.683	1.864	-0.181
100	32	1.720	1.901	-0.181
100	33	1.758	1.920	-0.162
100	34	1.683	1.827	-0.144
100	35	1.646	1.808	-0.162
100	36	1.664	1.845	-0.181
100	37	1.646	1.808	-0.162
100	38	1.795	1.808	-0.013
100	39	1.664	1.845	-0.181
100	41	1.646	1.808	-0.162
100	42	1.702	1.864	-0.162
100	43	1.664	1.808	-0.144
100	44	1.664	1.827	-0.163
	Max	1.795	1.920	0.014
	Average	1.689	1.810	-0.121
	Min	1.627	1.651	-0.200
	Std Dev	0.038	0.068	0.066



	IIL_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.651	1.750	1.825	1.715
Average	1.688	1.787	1.858	1.832
Max	1.744	1.843	1.899	1.920
UL	15.000	15.000	15.000	15.000



HDR Biased TID Report
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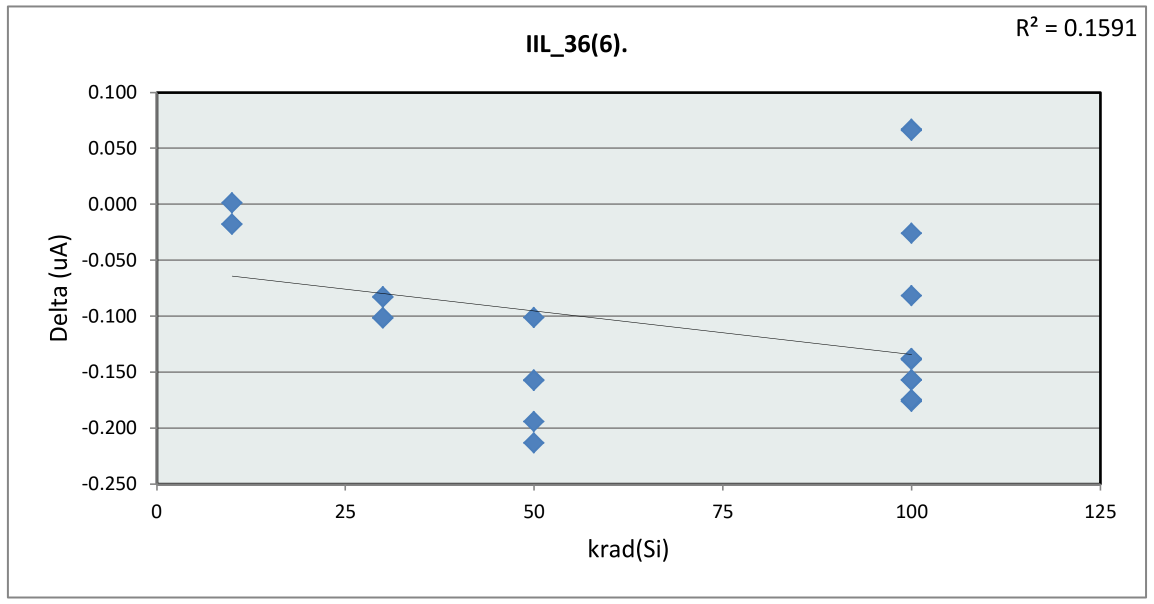
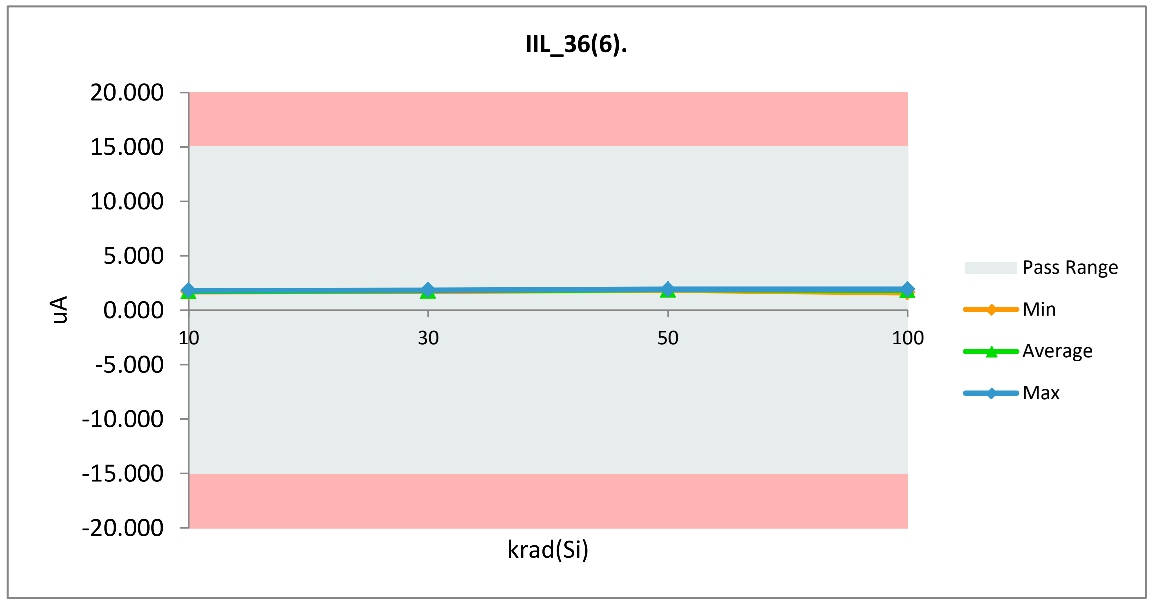
	IIL_36(6).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.678	1.696	-0.018
10	2	1.715	1.733	-0.018
10	3	1.678	1.696	-0.018
10	4	1.789	1.807	-0.018
10	5	1.715	1.714	0.001
30	1	1.695	1.778	-0.083
30	2	1.769	1.871	-0.102
30	3	1.676	1.778	-0.102
30	4	1.657	1.759	-0.102
30	5	1.676	1.759	-0.083
50	11	1.750	1.852	-0.102
50	12	1.695	1.908	-0.213
50	13	1.695	1.852	-0.157
50	14	1.788	1.945	-0.157
50	15	1.657	1.852	-0.195
100	22	1.715	1.890	-0.175
100	23	1.770	1.909	-0.139
100	24	1.752	1.909	-0.157
100	25	1.659	1.797	-0.138
100	26	1.715	1.853	-0.138
100	27	1.659	1.741	-0.082
100	28	1.659	1.685	-0.026
100	29	1.696	1.629	0.067
100	30	1.640	1.816	-0.176
100	31	1.696	1.872	-0.176
100	32	1.752	1.909	-0.157
100	33	1.808	1.946	-0.138
100	34	1.678	1.835	-0.157
100	35	1.659	1.797	-0.138
100	36	1.659	1.816	-0.157
100	37	1.659	1.816	-0.157
100	38	1.826	1.760	0.066
100	39	1.678	1.853	-0.175
100	41	1.659	1.816	-0.157
100	42	1.715	1.872	-0.157
100	43	1.659	1.816	-0.157
100	44	1.678	1.835	-0.157
	Max	1.826	1.946	0.067
	Average	1.703	1.815	-0.112
	Min	1.640	1.629	-0.213
	Std Dev	0.049	0.076	0.071



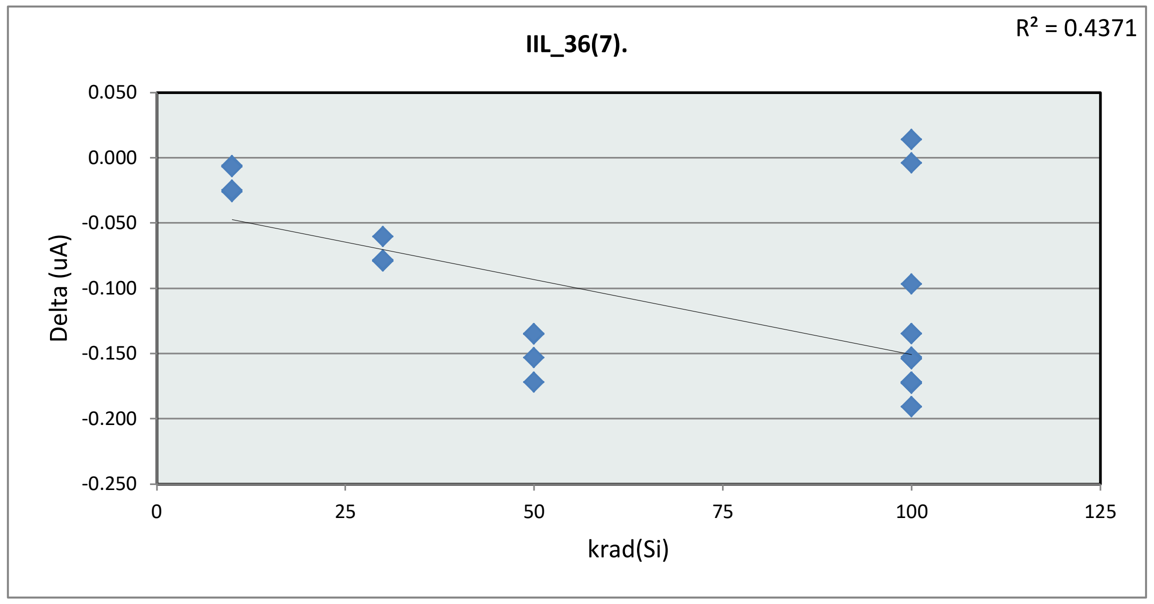
	IIL_36(6).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.696	1.759	1.852	1.629
Average	1.729	1.789	1.882	1.826
Max	1.807	1.871	1.945	1.946
UL	15.000	15.000	15.000	15.000



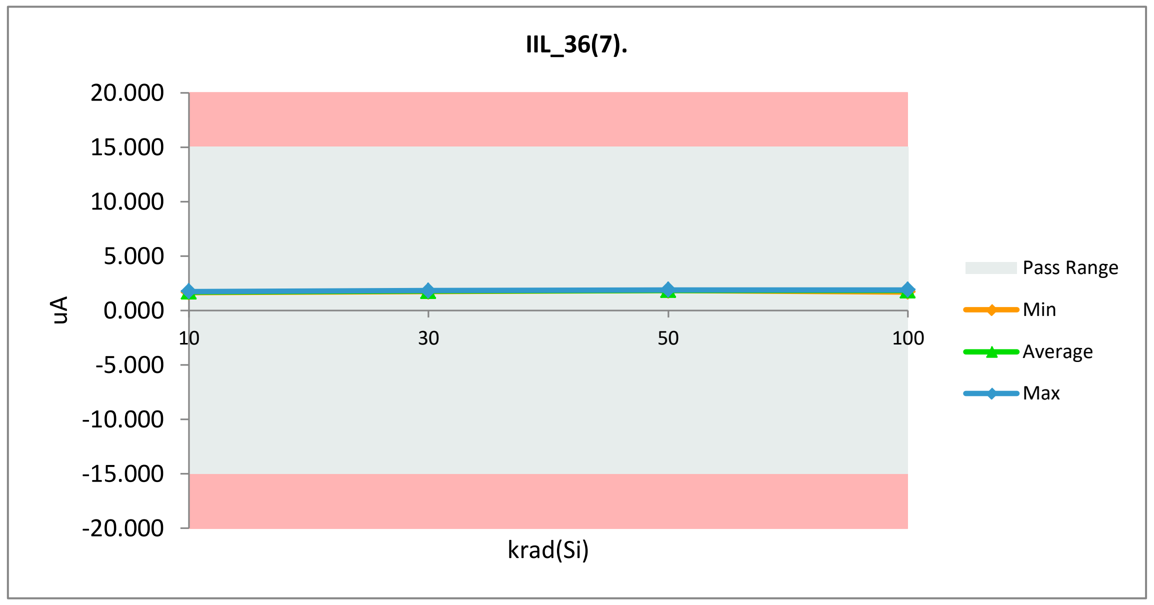
HDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(7).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.669	1.695	-0.026
10	2	1.688	1.713	-0.025
10	3	1.669	1.676	-0.007
10	4	1.763	1.769	-0.006
10	5	1.688	1.695	-0.007
30	1	1.710	1.789	-0.079
30	2	1.747	1.826	-0.079
30	3	1.710	1.789	-0.079
30	4	1.672	1.733	-0.061
30	5	1.672	1.751	-0.079
50	11	1.728	1.863	-0.135
50	12	1.691	1.863	-0.172
50	13	1.710	1.845	-0.135
50	14	1.747	1.900	-0.153
50	15	1.691	1.826	-0.135
100	22	1.707	1.879	-0.172
100	23	1.744	1.898	-0.154
100	24	1.725	1.898	-0.173
100	25	1.669	1.823	-0.154
100	26	1.707	1.842	-0.135
100	27	1.651	1.786	-0.135
100	28	1.651	1.748	-0.097
100	29	1.707	1.711	-0.004
100	30	1.632	1.823	-0.191
100	31	1.688	1.860	-0.172
100	32	1.725	1.898	-0.173
100	33	1.763	1.916	-0.153
100	34	1.669	1.842	-0.173
100	35	1.651	1.823	-0.172
100	36	1.688	1.823	-0.135
100	37	1.651	1.823	-0.172
100	38	1.800	1.786	0.014
100	39	1.688	1.842	-0.154
100	41	1.632	1.823	-0.191
100	42	1.688	1.860	-0.172
100	43	1.651	1.823	-0.172
100	44	1.669	1.823	-0.154
	Max	1.800	1.916	0.014
	Average	1.695	1.813	-0.118
	Min	1.632	1.676	-0.191
	Std Dev	0.039	0.063	0.063



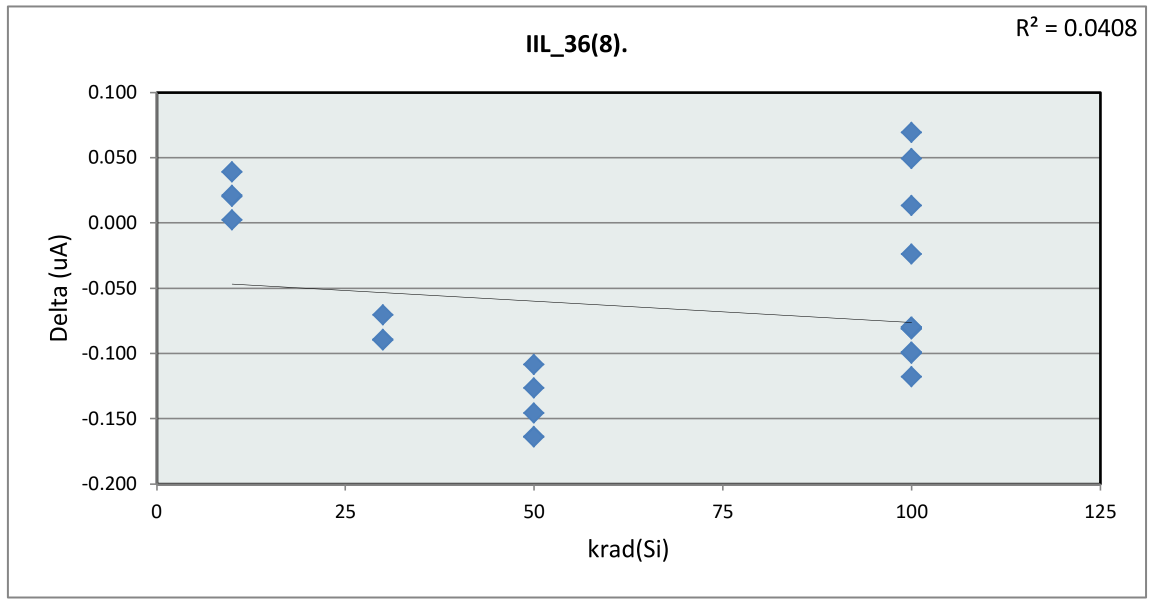
	IIL_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.676	1.733	1.826	1.711
Average	1.710	1.778	1.859	1.834
Max	1.769	1.826	1.900	1.916
UL	15.000	15.000	15.000	15.000



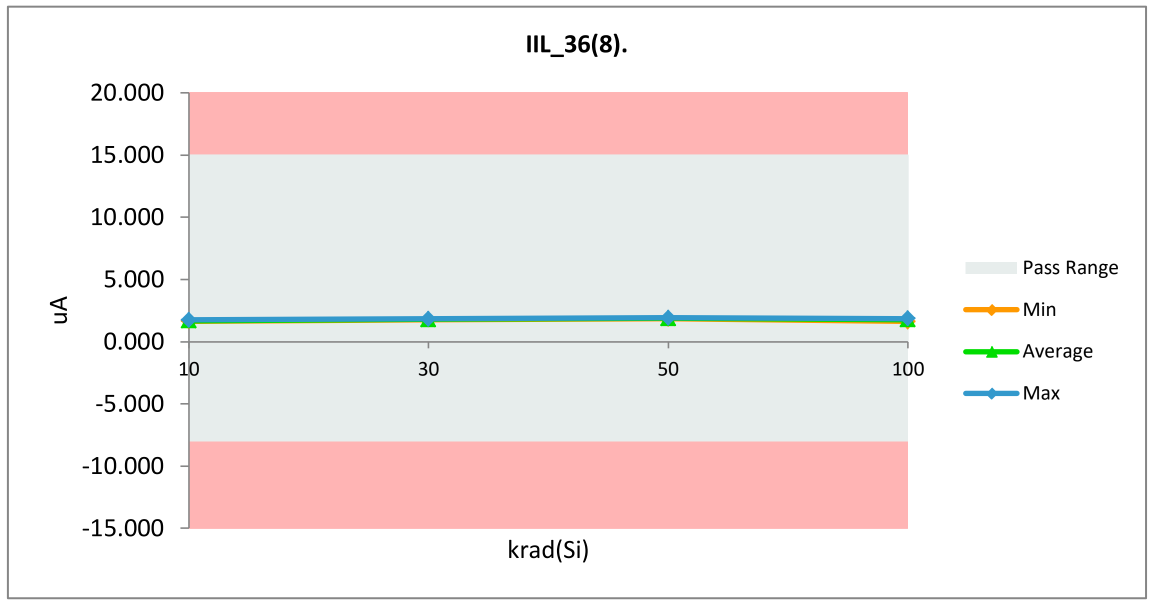
HDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(8).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.682	1.680	0.002
10	2	1.700	1.680	0.020
10	3	1.663	1.642	0.021
10	4	1.793	1.754	0.039
10	5	1.719	1.680	0.039
30	1	1.714	1.785	-0.071
30	2	1.752	1.841	-0.089
30	3	1.714	1.804	-0.090
30	4	1.677	1.767	-0.090
30	5	1.677	1.767	-0.090
50	11	1.752	1.860	-0.108
50	12	1.714	1.878	-0.164
50	13	1.714	1.841	-0.127
50	14	1.770	1.916	-0.146
50	15	1.696	1.860	-0.164
100	22	1.700	1.818	-0.118
100	23	1.756	1.837	-0.081
100	24	1.738	1.818	-0.080
100	25	1.663	1.744	-0.081
100	26	1.719	1.800	-0.081
100	27	1.682	1.706	-0.024
100	28	1.682	1.669	0.013
100	29	1.700	1.631	0.069
100	30	1.645	1.744	-0.099
100	31	1.700	1.800	-0.100
100	32	1.738	1.818	-0.080
100	33	1.775	1.856	-0.081
100	34	1.682	1.762	-0.080
100	35	1.663	1.744	-0.081
100	36	1.682	1.762	-0.080
100	37	1.663	1.762	-0.099
100	38	1.793	1.744	0.049
100	39	1.682	1.781	-0.099
100	41	1.663	1.744	-0.081
100	42	1.719	1.800	-0.081
100	43	1.663	1.744	-0.081
100	44	1.682	1.762	-0.080
	Max	1.793	1.916	0.069
	Average	1.706	1.773	-0.067
	Min	1.645	1.631	-0.164
	Std Dev	0.039	0.067	0.059

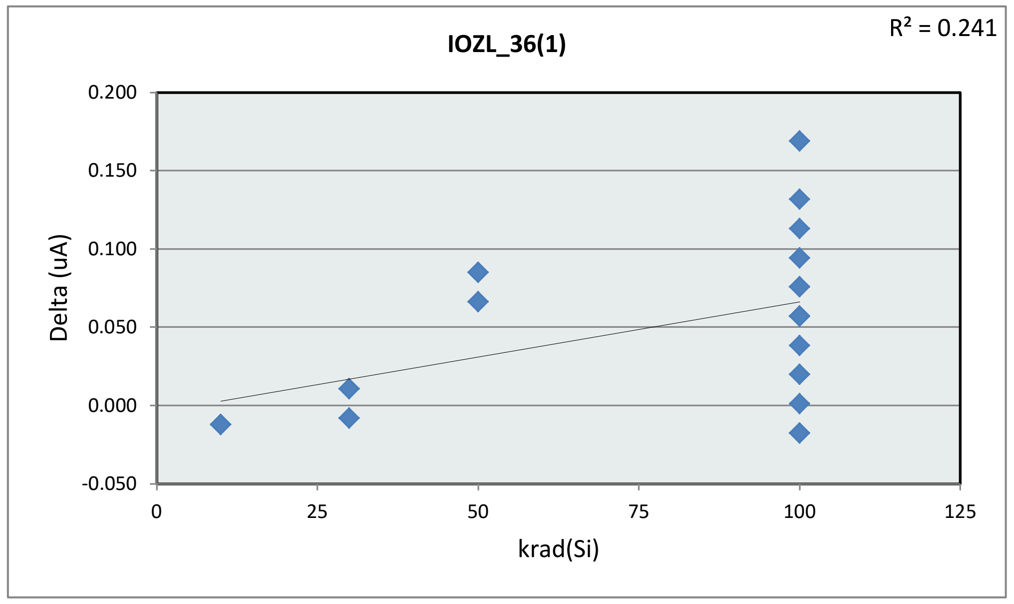


	IIL_36(8).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-8	uA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	1.642	1.767	1.841	1.631
Average	1.687	1.793	1.871	1.766
Max	1.754	1.841	1.916	1.856
UL	15.000	15.000	15.000	15.000

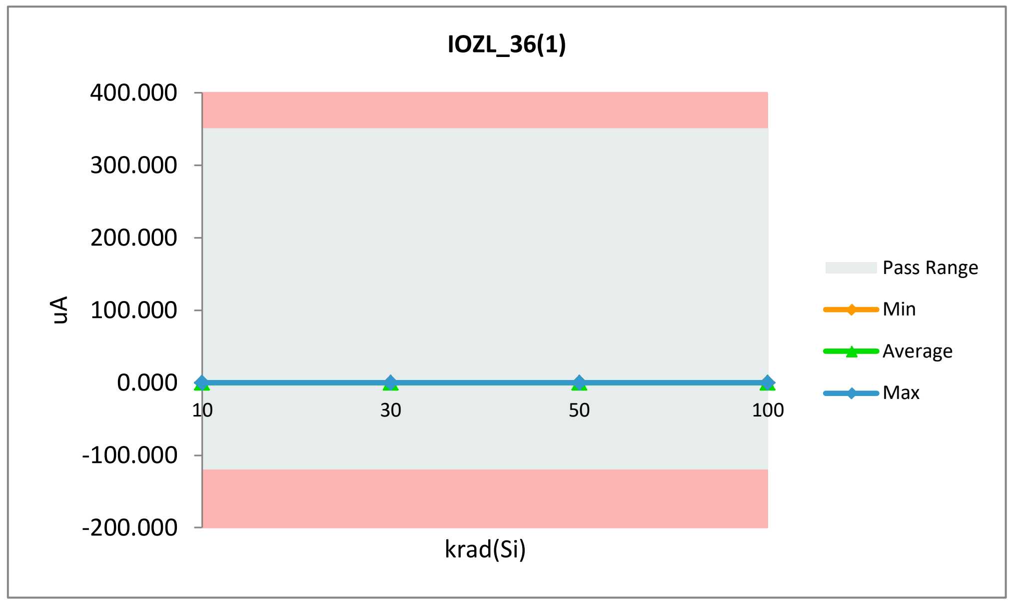


HDR Biased TID Report
SN55LVCP22A-SP

		IOZL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.028	-0.016	-0.012
10	2	-0.028	-0.016	-0.012
10	3	-0.028	-0.016	-0.012
10	4	-0.028	-0.016	-0.012
10	5	-0.028	-0.016	-0.012
30	1	0.022	0.011	0.011
30	2	0.003	-0.007	0.011
30	3	-0.015	-0.007	-0.008
30	4	0.003	-0.007	0.011
30	5	0.003	0.011	-0.008
50	11	-0.015	-0.100	0.085
50	12	-0.015	-0.082	0.066
50	13	-0.015	-0.100	0.085
50	14	0.022	-0.044	0.066
50	15	0.003	-0.082	0.085
100	22	-0.028	-0.085	0.057
100	23	-0.028	-0.067	0.038
100	24	-0.010	-0.067	0.057
100	25	-0.010	-0.067	0.057
100	26	-0.010	-0.029	0.020
100	27	-0.028	-0.011	-0.018
100	28	-0.028	-0.011	-0.018
100	29	-0.028	-0.011	-0.018
100	30	-0.028	-0.141	0.113
100	31	-0.010	-0.085	0.076
100	32	-0.010	-0.067	0.057
100	33	-0.028	-0.085	0.057
100	34	-0.028	-0.104	0.076
100	35	-0.010	-0.085	0.076
100	36	-0.028	-0.122	0.094
100	37	-0.028	-0.048	0.020
100	38	-0.010	-0.011	0.001
100	39	-0.028	-0.197	0.169
100	41	-0.010	-0.178	0.169
100	42	-0.010	-0.141	0.132
100	43	-0.028	-0.122	0.094
100	44	-0.028	-0.085	0.057
	Max	0.022	0.011	0.169
	Average	-0.016	-0.062	0.046
	Min	-0.028	-0.197	-0.018
	Std Dev	0.014	0.053	0.052



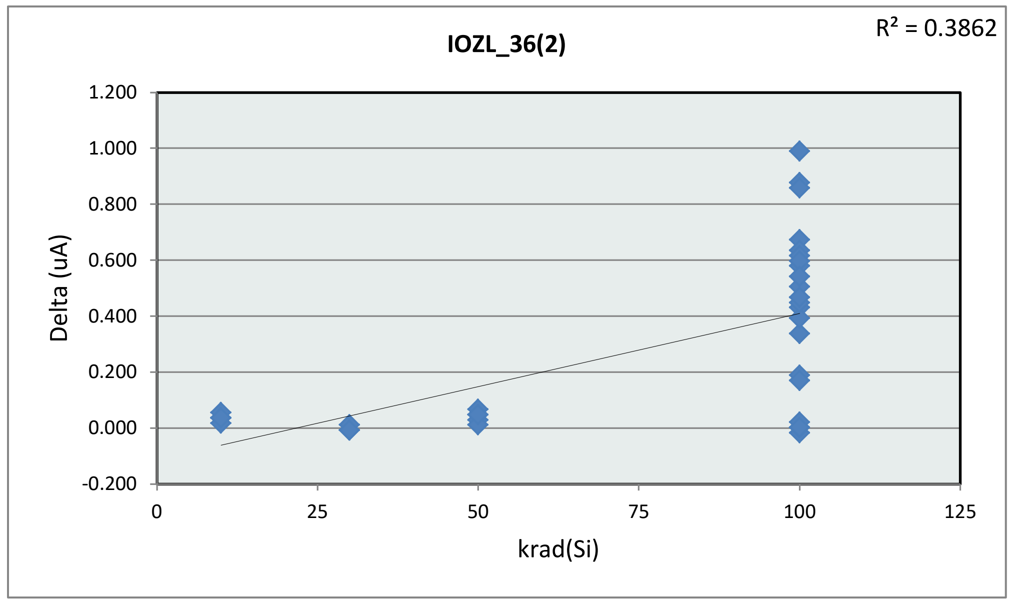
	IOZL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.016	-0.007	-0.100	-0.197
Average	-0.016	0.000	-0.082	-0.083
Max	-0.016	0.011	-0.044	-0.011
UL	350.000	350.000	350.000	350.000



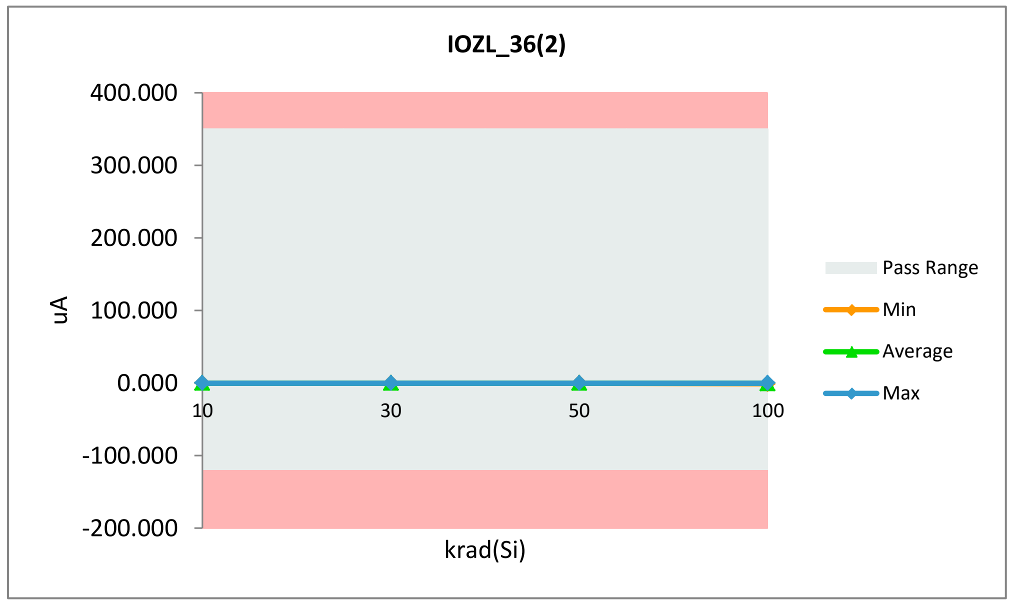
HDR Biased TID Report
SN55LVCP22A-SP

	IOZL_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.008	-0.027	0.036
10	2	0.008	-0.046	0.054
10	3	-0.010	-0.046	0.036
10	4	-0.010	-0.027	0.017
10	5	-0.010	-0.046	0.036
30	1	-0.005	0.003	-0.008
30	2	-0.005	0.003	-0.008
30	3	-0.005	0.003	-0.008
30	4	0.013	0.003	0.011
30	5	-0.005	0.003	-0.008
50	11	-0.005	-0.072	0.066
50	12	-0.005	-0.035	0.029
50	13	-0.005	-0.053	0.048
50	14	-0.005	-0.016	0.011
50	15	-0.005	-0.053	0.048
100	22	-0.010	-0.682	0.672
100	23	-0.010	-0.645	0.635
100	24	-0.010	-0.440	0.430
100	25	0.008	-0.180	0.188
100	26	-0.010	-0.031	0.020
100	27	-0.010	0.007	-0.017
100	28	-0.010	-0.012	0.002
100	29	0.008	0.007	0.002
100	30	0.008	-0.571	0.579
100	31	0.008	-0.329	0.337
100	32	-0.010	-0.626	0.616
100	33	-0.010	-0.403	0.393
100	34	-0.010	-0.459	0.449
100	35	0.008	-0.496	0.504
100	36	-0.010	-0.608	0.598
100	37	-0.010	-0.180	0.169
100	38	-0.010	-0.012	0.002
100	39	-0.010	-0.999	0.989
100	41	-0.010	-0.887	0.877
100	42	0.008	-0.850	0.858
100	43	0.008	-0.459	0.467
100	44	-0.010	-0.552	0.542
	Max	0.013	0.007	0.989
	Average	-0.004	-0.265	0.261
	Min	-0.010	-0.999	-0.017
	Std Dev	0.008	0.307	0.307



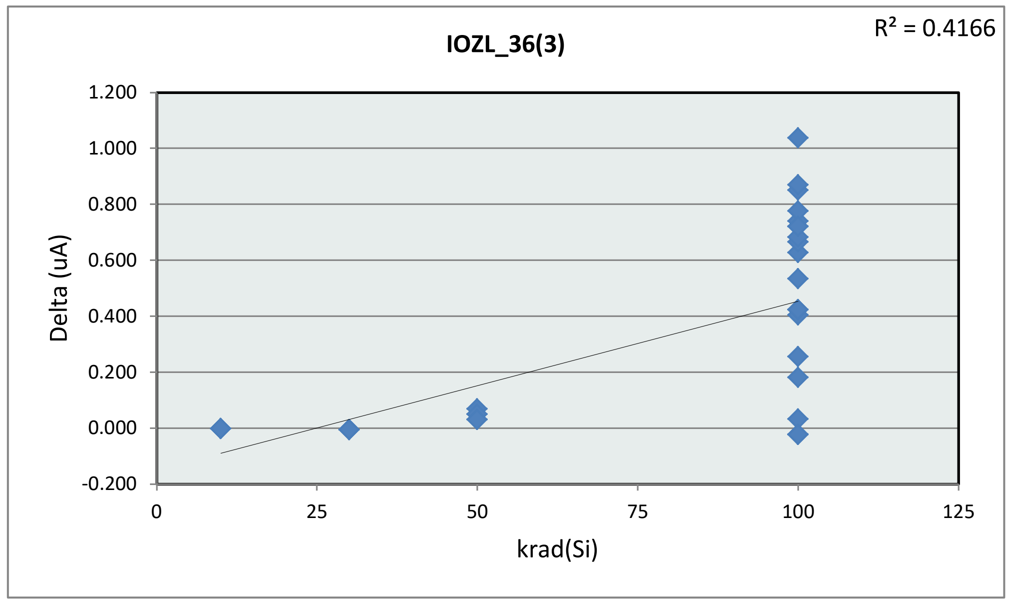
	IOZL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.046	0.003	-0.072	-0.999
Average	-0.039	0.003	-0.046	-0.428
Max	-0.027	0.003	-0.016	0.007
UL	350.000	350.000	350.000	350.000



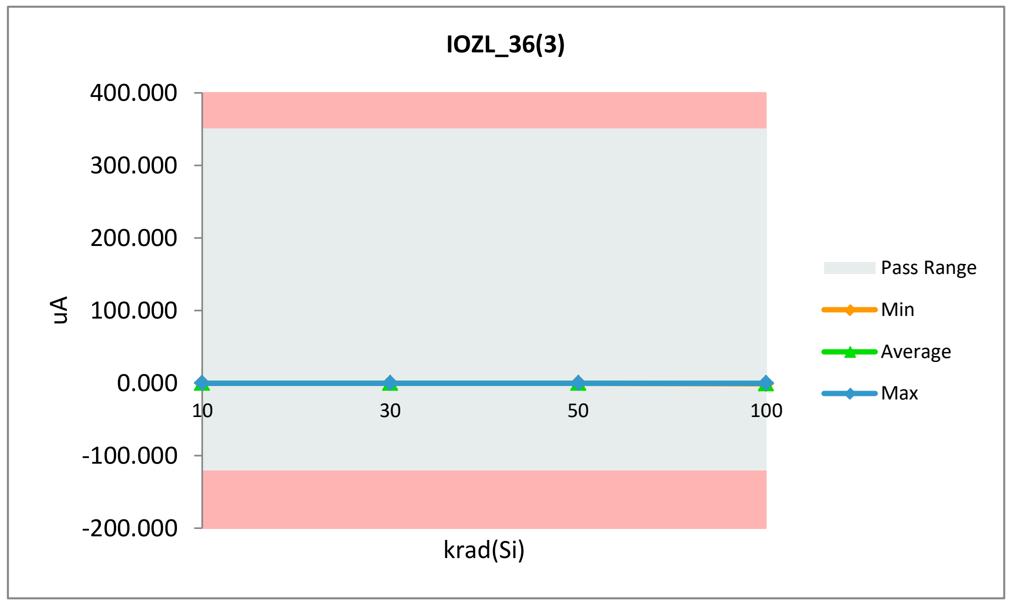
HDR Biased TID Report
SN55LVCP22A-SP

	IOZL_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.002	0.001	-0.003
10	2	-0.002	0.001	-0.003
10	3	-0.002	0.001	-0.003
10	4	-0.002	0.001	-0.003
10	5	-0.002	0.001	-0.003
30	1	-0.016	-0.010	-0.006
30	2	-0.016	-0.010	-0.006
30	3	-0.016	-0.010	-0.006
30	4	-0.016	-0.010	-0.006
30	5	-0.016	-0.010	-0.006
50	11	-0.016	-0.084	0.068
50	12	-0.016	-0.066	0.050
50	13	-0.016	-0.066	0.050
50	14	-0.016	-0.047	0.031
50	15	-0.016	-0.047	0.031
100	22	-0.002	-0.853	0.851
100	23	-0.002	-0.871	0.869
100	24	-0.002	-0.406	0.404
100	25	-0.002	-0.257	0.255
100	26	-0.002	-0.034	0.032
100	27	-0.002	0.022	-0.024
100	28	-0.002	0.022	-0.024
100	29	-0.002	0.022	-0.024
100	30	-0.002	-0.741	0.739
100	31	-0.002	-0.778	0.776
100	32	-0.002	-0.629	0.627
100	33	-0.002	-0.425	0.423
100	34	-0.002	-0.425	0.423
100	35	-0.002	-0.425	0.423
100	36	-0.002	-0.666	0.665
100	37	-0.002	-0.183	0.181
100	38	-0.002	0.022	-0.024
100	39	-0.002	-1.039	1.037
100	41	-0.002	-0.722	0.720
100	42	-0.002	-0.685	0.683
100	43	-0.002	-0.722	0.720
100	44	-0.002	-0.536	0.534
	Max	-0.002	0.022	1.037
	Average	-0.006	-0.288	0.283
	Min	-0.016	-1.039	-0.024
	Std Dev	0.006	0.338	0.341

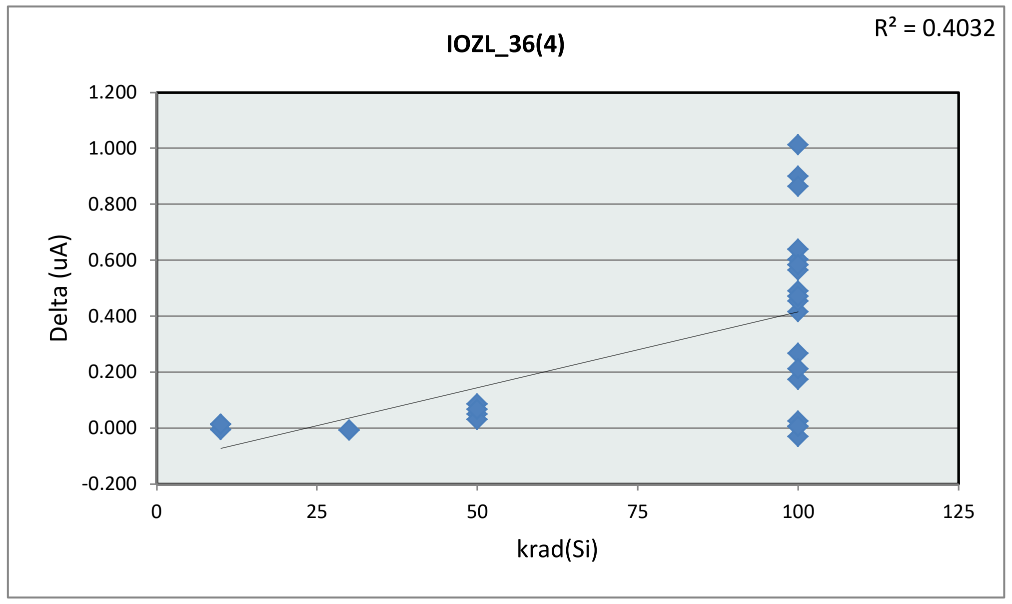


	IOZL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.001	-0.010	-0.084	-1.039
Average	0.001	-0.010	-0.062	-0.469
Max	0.001	-0.010	-0.047	0.022
UL	350.000	350.000	350.000	350.000

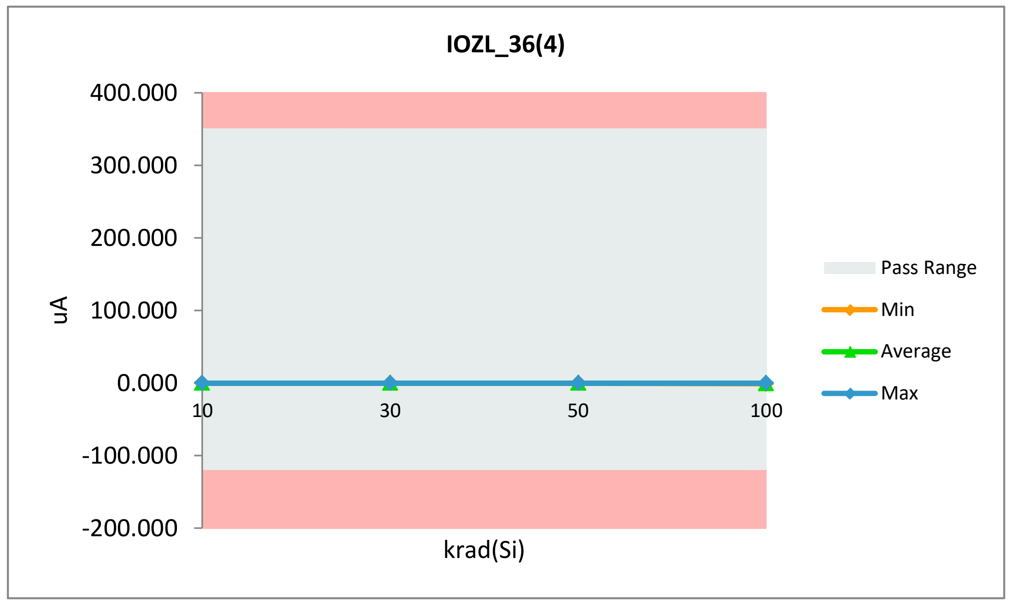


HDR Biased TID Report
SN55LVCP22A-SP

		IOZL_36(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		350	350	
Min Limit		-120	-120	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.007	-0.020	0.013
10	2	-0.007	-0.020	0.013
10	3	-0.007	-0.001	-0.006
10	4	-0.007	-0.001	-0.006
10	5	-0.007	-0.020	0.013
30	1	-0.019	-0.012	-0.007
30	2	-0.019	-0.012	-0.007
30	3	-0.019	-0.012	-0.007
30	4	-0.019	-0.012	-0.007
30	5	-0.019	-0.012	-0.007
50	11	-0.019	-0.105	0.086
50	12	-0.019	-0.068	0.049
50	13	-0.019	-0.105	0.086
50	14	-0.019	-0.049	0.030
50	15	-0.019	-0.086	0.067
100	22	-0.007	-0.907	0.900
100	23	-0.007	-0.870	0.863
100	24	-0.026	-0.442	0.416
100	25	-0.026	-0.199	0.174
100	26	-0.026	-0.050	0.025
100	27	-0.007	-0.013	0.006
100	28	-0.026	0.005	-0.031
100	29	-0.007	-0.013	0.006
100	30	-0.026	-0.628	0.602
100	31	-0.026	-0.516	0.490
100	32	-0.007	-0.591	0.583
100	33	-0.007	-0.460	0.453
100	34	-0.007	-0.274	0.267
100	35	-0.007	-0.479	0.472
100	36	-0.007	-0.646	0.639
100	37	-0.026	-0.237	0.211
100	38	-0.007	-0.013	0.006
100	39	-0.007	-1.019	1.012
100	41	-0.007	-0.646	0.639
100	42	-0.007	-0.572	0.565
100	43	-0.007	-0.479	0.472
100	44	-0.007	-0.591	0.583
	Max	-0.007	0.005	1.012
	Average	-0.014	-0.275	0.261
	Min	-0.026	-1.019	-0.031
	Std Dev	0.008	0.308	0.310

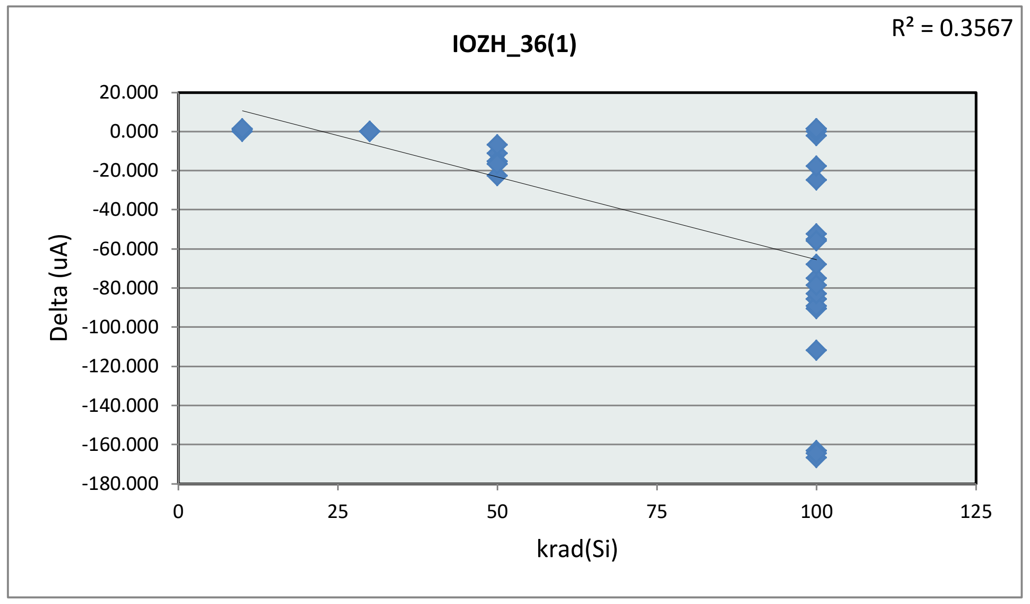


	IOZL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.020	-0.012	-0.105	-1.019
Average	-0.013	-0.012	-0.083	-0.438
Max	-0.001	-0.012	-0.049	0.005
UL	350.000	350.000	350.000	350.000

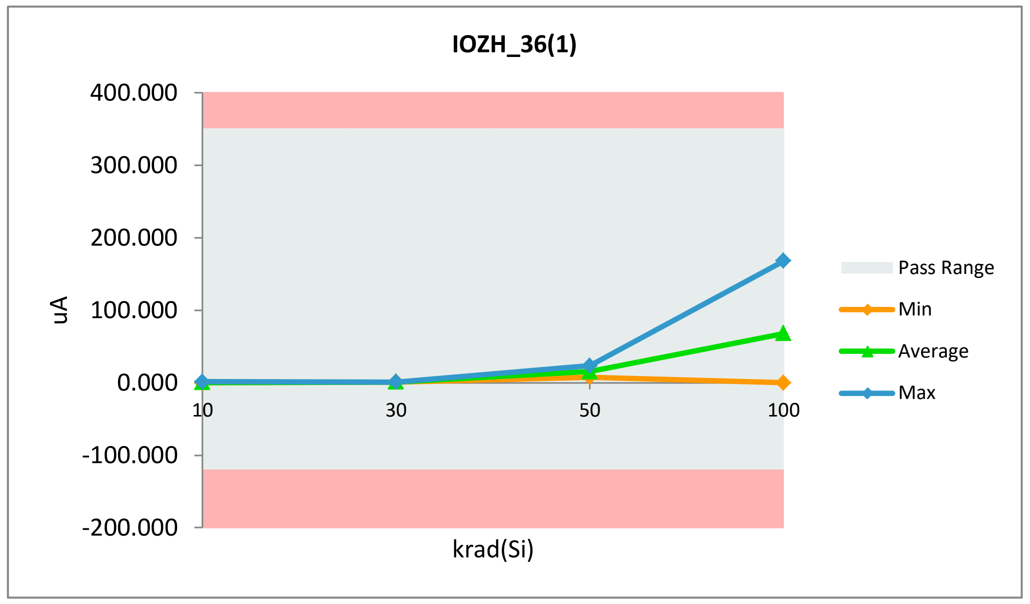


HDR Biased TID Report
SN55LVCP22A-SP

		IOZH_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.146	1.262	-0.116
10	2	1.146	0.071	1.075
10	3	1.146	0.071	1.075
10	4	1.146	0.071	1.075
10	5	1.446	0.071	1.375
30	1	1.008	0.979	0.029
30	2	0.971	0.979	-0.008
30	3	1.026	1.072	-0.046
30	4	1.008	1.016	-0.008
30	5	1.008	0.997	0.010
50	11	0.952	23.649	-22.697
50	12	0.989	12.231	-11.242
50	13	1.045	16.438	-15.393
50	14	0.915	7.724	-6.809
50	15	1.008	17.640	-16.632
100	22	1.146	86.894	-85.748
100	23	1.146	86.894	-85.748
100	24	0.845	55.905	-55.060
100	25	1.146	26.108	-24.962
100	26	1.146	3.462	-2.316
100	27	1.146	1.078	0.068
100	28	1.146	-0.114	1.260
100	29	1.146	-0.114	1.260
100	30	1.146	91.662	-90.516
100	31	1.146	53.521	-52.375
100	32	1.146	90.470	-89.324
100	33	1.146	57.097	-55.951
100	34	1.146	76.167	-75.021
100	35	1.146	69.016	-67.870
100	36	1.146	113.116	-111.970
100	37	1.146	18.956	-17.810
100	38	1.146	-0.114	1.260
100	39	1.146	167.943	-166.797
100	41	1.146	164.368	-163.222
100	42	1.146	165.560	-164.414
100	43	1.446	84.511	-83.065
100	44	1.146	79.743	-78.597
	Max	1.446	167.943	1.375
	Average	1.113	42.605	-41.493
	Min	0.845	-0.114	-166.797
	Std Dev	0.115	51.553	51.527



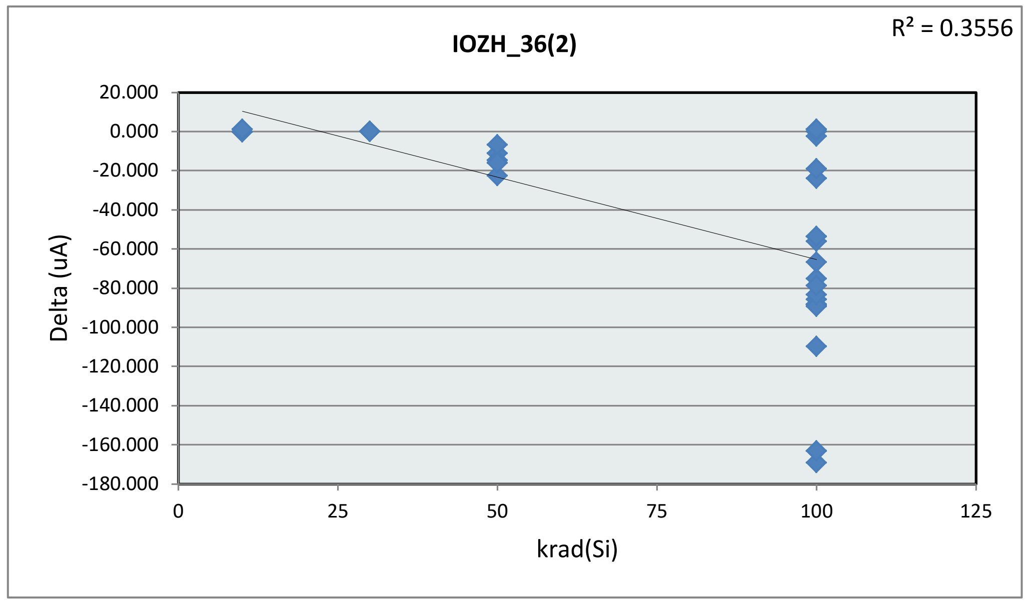
	IOZH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.071	0.979	7.724	-0.114
Average	0.309	1.009	15.536	67.824
Max	1.262	1.072	23.649	167.943
UL	350.000	350.000	350.000	350.000



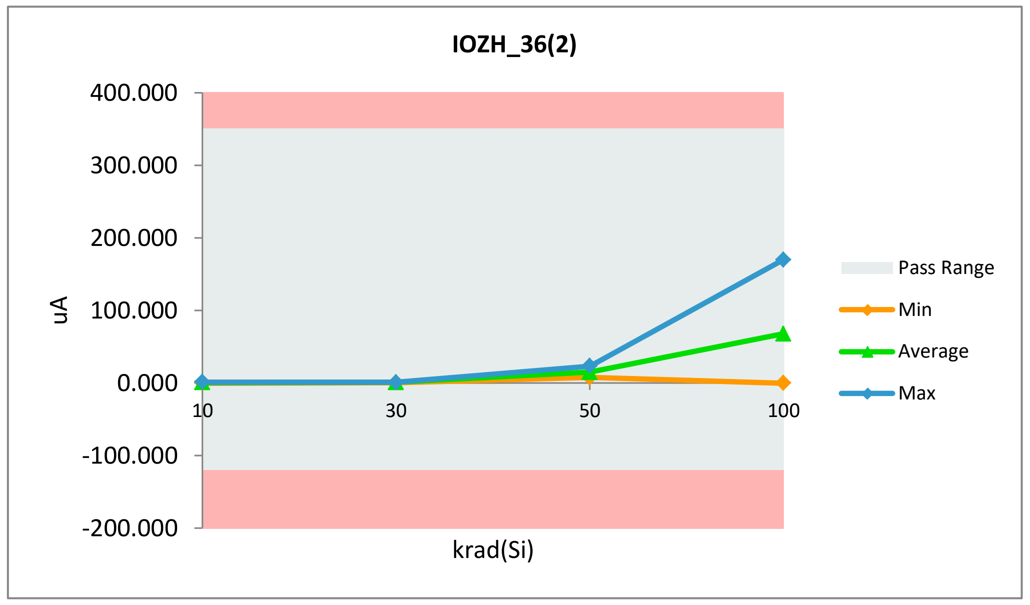
HDR Biased TID Report
SN55LVCP22A-SP

	IOZH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.135	1.373	-0.238
10	2	1.135	0.182	0.953
10	3	1.135	1.373	-0.238
10	4	1.135	1.373	-0.238
10	5	1.135	0.182	0.953
30	1	1.000	0.989	0.011
30	2	0.962	0.952	0.011
30	3	1.037	1.045	-0.008
30	4	1.000	1.026	-0.026
30	5	1.018	0.989	0.029
50	11	0.944	23.481	-22.537
50	12	1.000	12.057	-11.057
50	13	1.037	15.664	-14.627
50	14	0.925	7.848	-6.923
50	15	1.018	17.168	-16.150
100	22	1.135	86.965	-85.830
100	23	0.835	89.347	-88.512
100	24	1.135	57.188	-56.053
100	25	1.135	25.029	-23.894
100	26	1.135	3.590	-2.455
100	27	1.135	1.207	-0.072
100	28	1.135	0.016	1.119
100	29	1.135	1.207	-0.072
100	30	1.135	89.347	-88.212
100	31	1.135	54.806	-53.671
100	32	1.135	90.538	-89.403
100	33	1.135	54.806	-53.671
100	34	1.135	76.245	-75.110
100	35	1.135	67.908	-66.773
100	36	1.135	110.787	-109.652
100	37	1.135	20.265	-19.130
100	38	1.135	0.016	1.119
100	39	1.135	170.340	-169.205
100	41	1.135	164.385	-163.250
100	42	1.135	164.385	-163.250
100	43	1.135	84.583	-83.448
100	44	1.135	79.819	-78.684
	Max	1.135	170.340	1.119
	Average	1.089	42.662	-41.573
	Min	0.835	0.016	-169.205
	Std Dev	0.079	51.454	51.435



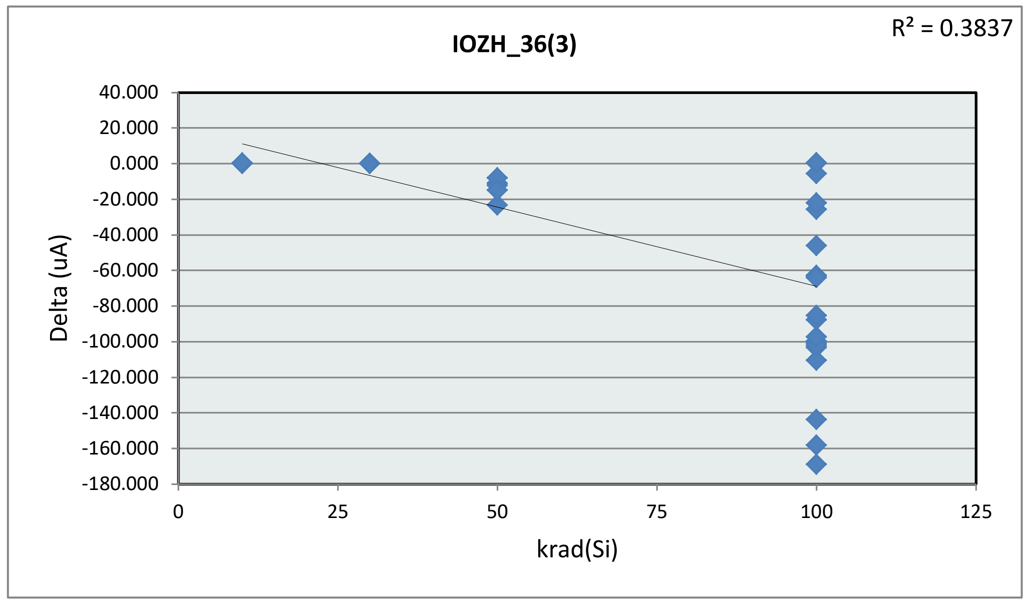
	IOZH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.182	0.952	7.848	0.016
Average	0.897	1.000	15.244	67.854
Max	1.373	1.045	23.481	170.340
UL	350.000	350.000	350.000	350.000



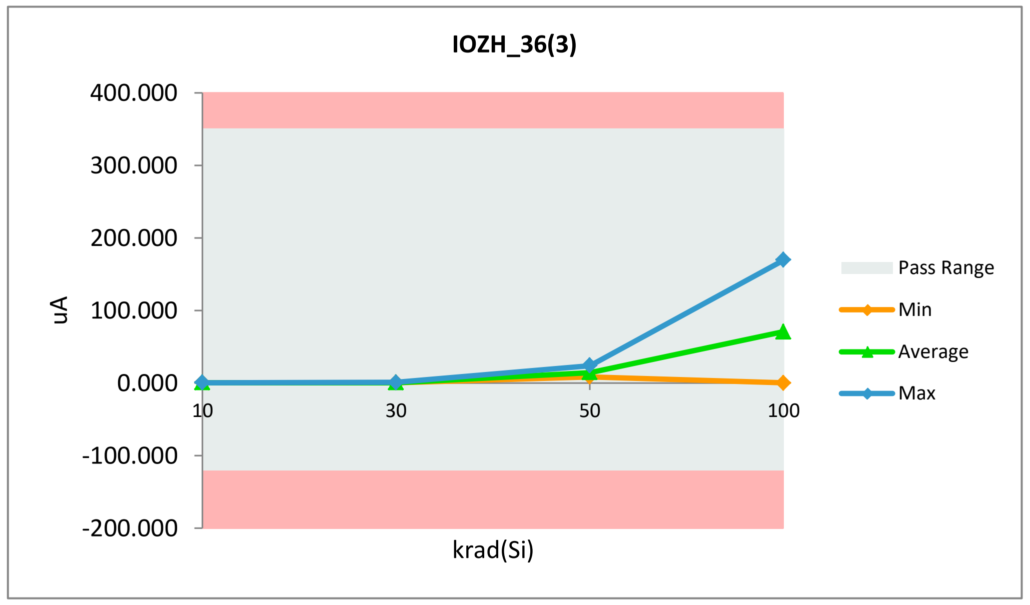
HDR Biased TID Report
SN55LVCP22A-SP

	IOZH_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	0.716	0.846	-0.129
10	2	0.716	0.846	-0.129
10	3	0.716	0.846	-0.129
10	4	0.716	0.846	-0.129
10	5	1.017	0.846	0.171
30	1	0.973	0.978	-0.005
30	2	0.935	0.922	0.013
30	3	0.973	0.978	-0.005
30	4	0.973	0.959	0.013
30	5	0.973	1.034	-0.061
50	11	0.898	24.270	-23.372
50	12	0.973	11.919	-10.946
50	13	0.973	13.124	-12.151
50	14	0.879	8.907	-8.028
50	15	0.973	15.836	-14.863
100	22	0.716	144.680	-143.964
100	23	0.716	158.993	-158.277
100	24	0.716	63.570	-62.854
100	25	0.716	26.594	-25.878
100	26	0.716	6.316	-5.600
100	27	0.716	0.352	0.364
100	28	0.716	0.352	0.364
100	29	0.716	0.352	0.364
100	30	0.716	100.547	-99.831
100	31	0.716	104.125	-103.409
100	32	0.716	101.740	-101.024
100	33	0.716	63.570	-62.854
100	34	0.716	46.871	-46.155
100	35	0.716	64.763	-64.047
100	36	0.716	111.282	-110.566
100	37	0.716	23.015	-22.299
100	38	0.716	0.352	0.364
100	39	0.716	169.729	-169.013
100	41	0.716	102.932	-102.216
100	42	0.716	98.161	-97.445
100	43	0.716	88.619	-87.903
100	44	0.716	86.233	-85.517
	Max	1.017	169.729	0.364
	Average	0.788	44.495	-43.707
	Min	0.716	0.352	-169.013
	Std Dev	0.114	52.166	52.220



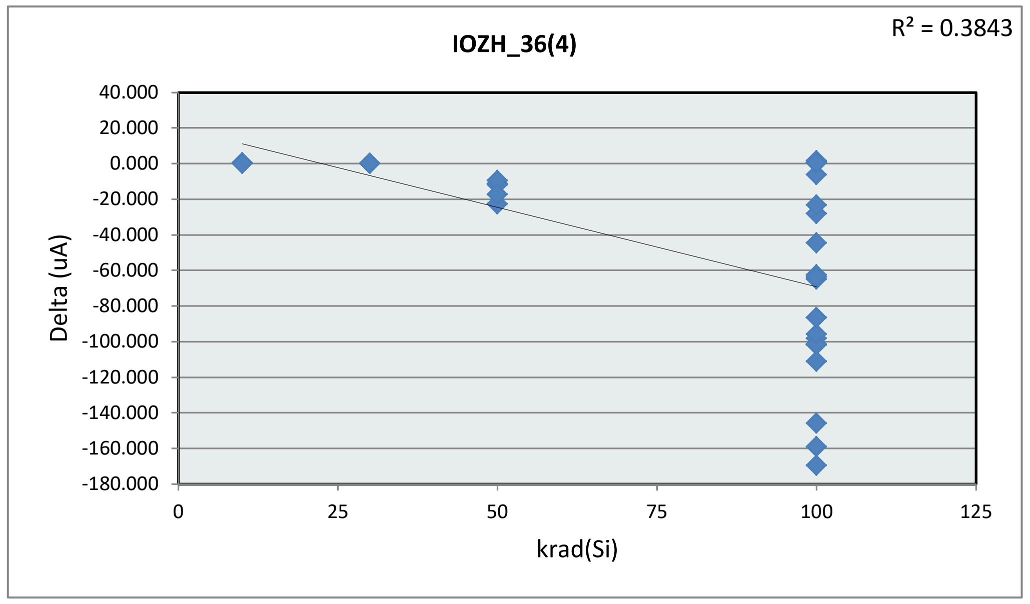
	IOZH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.846	0.922	8.907	0.352
Average	0.846	0.974	14.811	71.052
Max	0.846	1.034	24.270	169.729
UL	350.000	350.000	350.000	350.000



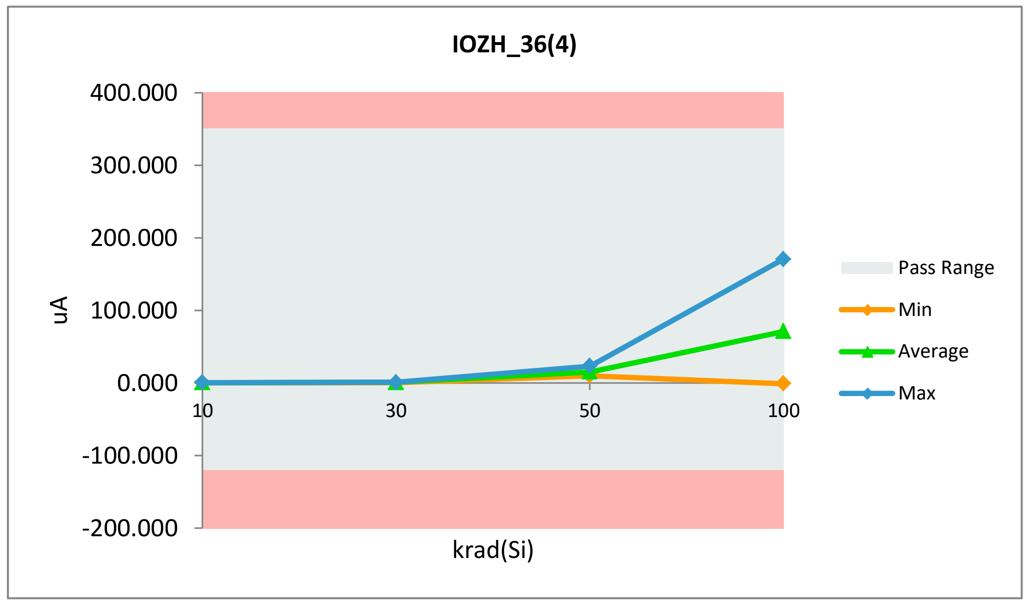
HDR Biased TID Report
SN55LVCP22A-SP

	IOZH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.219	0.787	0.432
10	2	0.919	0.787	0.132
10	3	1.219	0.787	0.432
10	4	1.219	0.787	0.432
10	5	0.919	0.787	0.132
30	1	0.985	1.011	-0.026
30	2	0.948	0.918	0.030
30	3	0.985	0.993	-0.007
30	4	0.985	0.974	0.012
30	5	0.985	1.123	-0.138
50	11	0.930	23.670	-22.740
50	12	0.985	12.262	-11.277
50	13	1.004	12.862	-11.858
50	14	0.911	10.461	-9.550
50	15	1.004	18.266	-17.262
100	22	0.919	146.955	-146.036
100	23	0.919	160.055	-159.136
100	24	0.919	63.595	-62.676
100	25	0.919	29.060	-28.141
100	26	1.219	7.625	-6.406
100	27	0.919	0.479	0.439
100	28	1.219	0.479	0.740
100	29	0.919	-0.711	1.630
100	30	0.919	99.321	-98.402
100	31	0.919	102.893	-101.974
100	32	1.219	102.893	-101.674
100	33	0.919	65.977	-65.058
100	34	1.219	45.732	-44.513
100	35	0.919	64.786	-63.867
100	36	1.219	112.420	-111.201
100	37	0.919	24.297	-23.378
100	38	0.919	0.479	0.439
100	39	1.219	170.772	-169.553
100	41	1.219	102.893	-101.674
100	42	0.919	96.939	-96.020
100	43	0.919	87.412	-86.493
100	44	0.919	87.412	-86.493
	Max	1.219	170.772	1.630
	Average	1.014	44.817	-43.803
	Min	0.911	-0.711	-169.553
	Std Dev	0.129	52.310	52.306

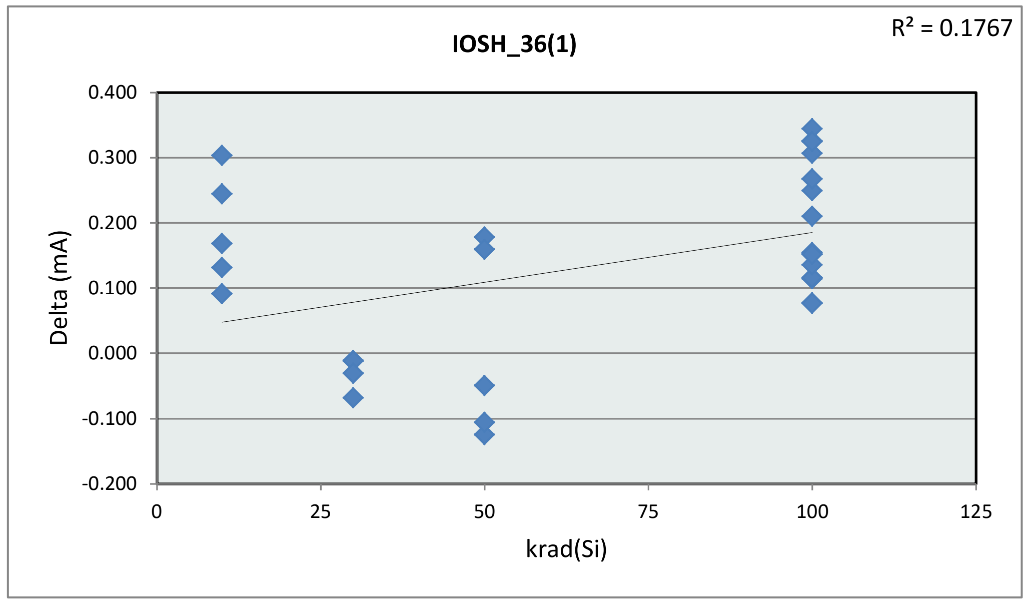


	IOZH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.787	0.918	10.461	-0.711
Average	0.787	1.004	15.504	71.444
Max	0.787	1.123	23.670	170.772
UL	350.000	350.000	350.000	350.000

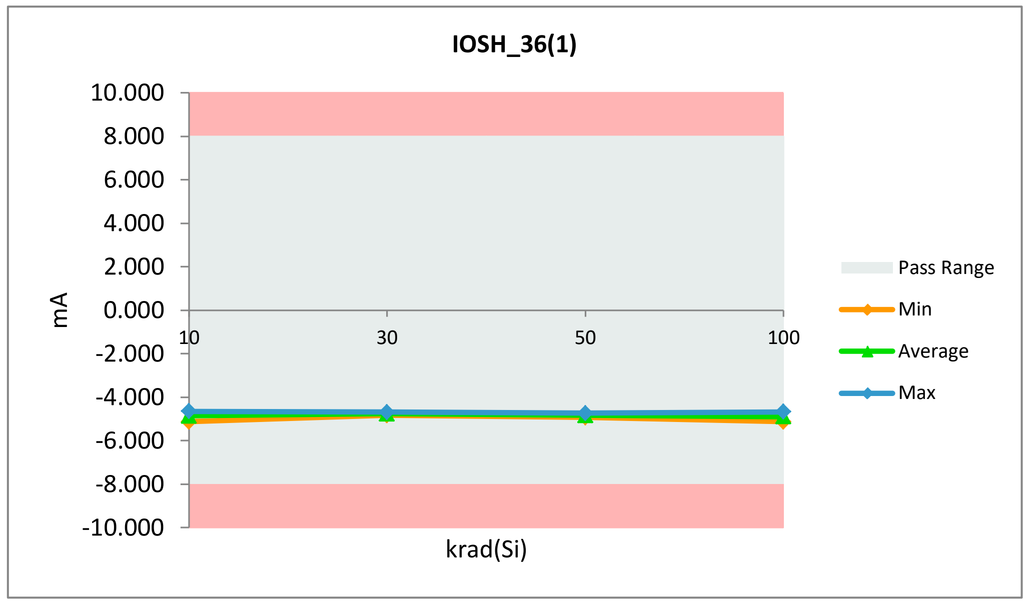


HDR Biased TID Report
SN55LVCP22A-SP

		IOSH_36(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	-4.557	-4.648	0.091
10	2	-4.765	-4.896	0.131
10	3	-4.595	-4.839	0.244
10	4	-4.633	-4.801	0.168
10	5	-4.822	-5.125	0.303
30	1	-4.845	-4.834	-0.011
30	2	-4.713	-4.701	-0.012
30	3	-4.827	-4.796	-0.031
30	4	-4.713	-4.682	-0.031
30	5	-4.845	-4.777	-0.068
50	11	-4.940	-4.815	-0.125
50	12	-4.751	-4.929	0.178
50	13	-4.845	-4.739	-0.106
50	14	-4.808	-4.758	-0.050
50	15	-4.751	-4.910	0.159
100	22	-4.671	-4.881	0.210
100	23	-4.784	-5.090	0.306
100	24	-4.652	-4.728	0.076
100	25	-4.727	-5.052	0.325
100	26	-4.841	-4.957	0.116
100	27	-4.879	-5.128	0.249
100	28	-4.803	-5.128	0.325
100	29	-4.765	-5.090	0.325
100	30	-4.519	-4.671	0.152
100	31	-4.614	-4.881	0.267
100	32	-4.576	-4.690	0.114
100	33	-4.727	-4.804	0.077
100	34	-4.803	-4.919	0.116
100	35	-4.727	-4.881	0.154
100	36	-4.708	-5.052	0.344
100	37	-4.822	-4.957	0.135
100	38	-4.652	-4.976	0.324
100	39	-4.519	-4.671	0.152
100	41	-4.633	-4.900	0.267
100	42	-4.595	-4.747	0.152
100	43	-4.576	-4.728	0.152
100	44	-4.671	-4.747	0.076
	Max	-4.519	-4.648	0.344
	Average	-4.721	-4.863	0.142
	Min	-4.940	-5.128	-0.125
	Std Dev	0.108	0.144	0.132



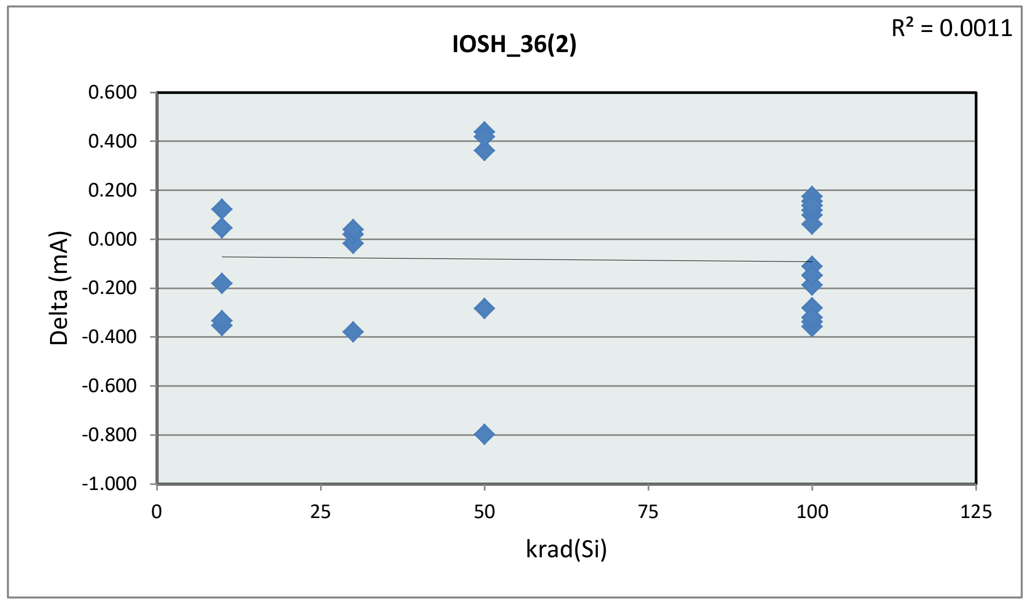
	IOSH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.125	-4.834	-4.929	-5.128
Average	-4.862	-4.758	-4.830	-4.894
Max	-4.648	-4.682	-4.739	-4.671
UL	8.000	8.000	8.000	8.000



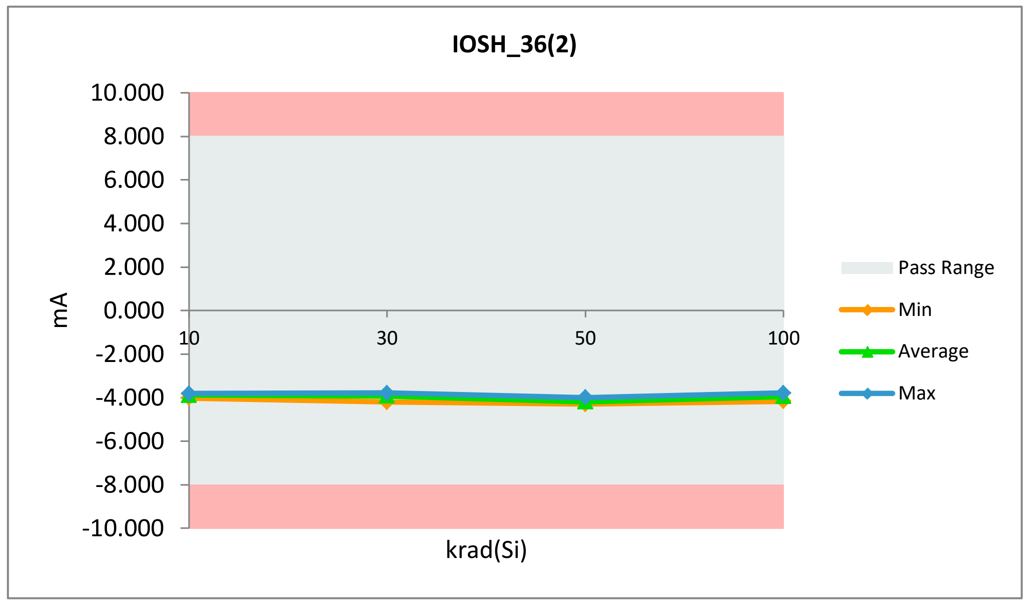
HDR Biased TID Report
SN55LVCP22A-SP

	IOSH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	-4.160	-3.806	-0.354
10	2	-3.799	-3.844	0.045
10	3	-3.685	-3.806	0.121
10	4	-4.198	-4.016	-0.182
10	5	-4.293	-3.959	-0.334
30	1	-3.839	-3.858	0.019
30	2	-4.218	-4.200	-0.018
30	3	-3.896	-3.915	0.019
30	4	-3.744	-3.782	0.038
30	5	-4.237	-3.858	-0.379
50	11	-4.275	-3.991	-0.284
50	12	-3.820	-4.257	0.437
50	13	-4.997	-4.200	-0.797
50	14	-3.839	-4.200	0.361
50	15	-3.877	-4.295	0.418
100	22	-3.723	-3.897	0.174
100	23	-4.274	-4.087	-0.187
100	24	-3.723	-3.821	0.098
100	25	-4.312	-4.164	-0.148
100	26	-4.274	-3.992	-0.282
100	27	-4.331	-3.973	-0.358
100	28	-3.894	-4.049	0.155
100	29	-3.742	-3.878	0.136
100	30	-3.704	-3.859	0.155
100	31	-3.913	-3.973	0.060
100	32	-4.160	-3.821	-0.339
100	33	-4.198	-3.859	-0.339
100	34	-4.274	-3.954	-0.320
100	35	-4.198	-4.011	-0.187
100	36	-3.818	-3.935	0.117
100	37	-4.274	-3.992	-0.282
100	38	-3.951	-3.840	-0.111
100	39	-4.065	-3.916	-0.149
100	41	-3.761	-3.897	0.136
100	42	-4.198	-4.049	-0.149
100	43	-4.103	-3.783	-0.320
100	44	-4.160	-4.011	-0.149
	Max	-3.685	-3.782	0.437
	Average	-4.052	-3.966	-0.086
	Min	-4.997	-4.295	-0.797
	Std Dev	0.271	0.139	0.259



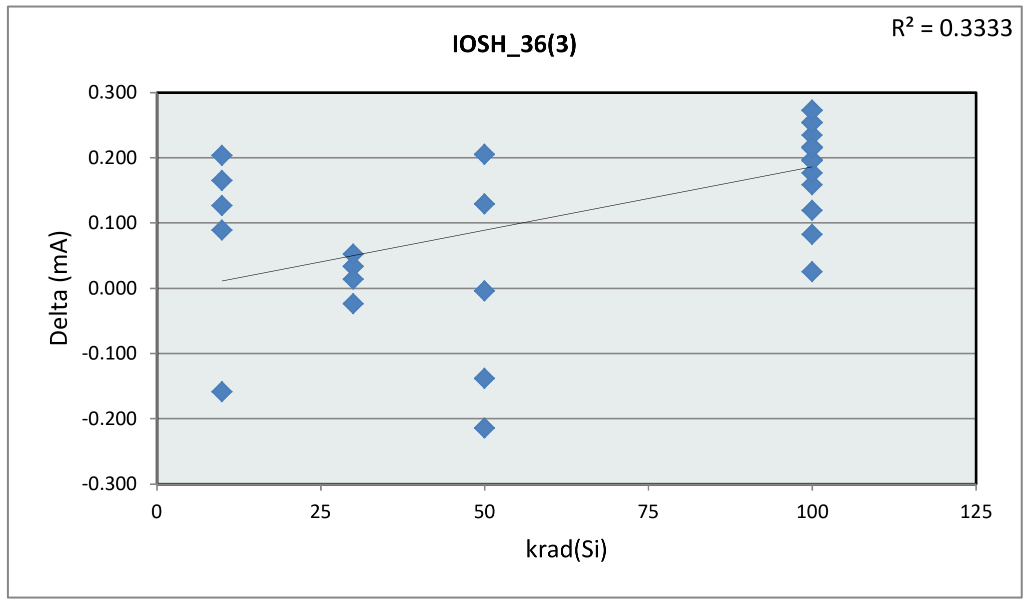
	IOSH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.016	-4.200	-4.295	-4.164
Average	-3.886	-3.923	-4.189	-3.944
Max	-3.806	-3.782	-3.991	-3.783
UL	8.000	8.000	8.000	8.000



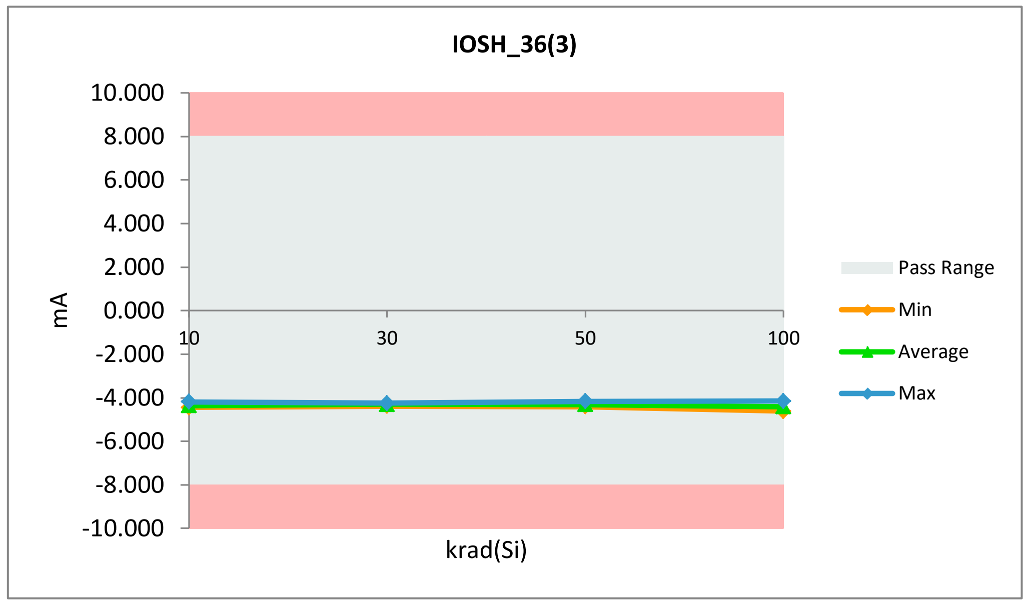
HDR Biased TID Report
SN55LVCP22A-SP

	IOSH_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.210	-4.375	0.165
10	2	-4.534	-4.375	-0.159
10	3	-4.058	-4.184	0.126
10	4	-4.248	-4.451	0.203
10	5	-4.305	-4.394	0.089
30	1	-4.240	-4.273	0.033
30	2	-4.278	-4.254	-0.024
30	3	-4.354	-4.388	0.034
30	4	-4.259	-4.273	0.014
30	5	-4.240	-4.292	0.052
50	11	-4.373	-4.235	-0.138
50	12	-4.164	-4.369	0.205
50	13	-4.373	-4.159	-0.214
50	14	-4.393	-4.388	-0.005
50	15	-4.278	-4.407	0.129
100	22	-4.096	-4.272	0.176
100	23	-4.362	-4.578	0.216
100	24	-4.210	-4.368	0.158
100	25	-4.286	-4.482	0.196
100	26	-4.286	-4.482	0.196
100	27	-4.362	-4.578	0.216
100	28	-4.324	-4.578	0.254
100	29	-4.077	-4.292	0.215
100	30	-4.096	-4.272	0.176
100	31	-4.096	-4.311	0.215
100	32	-4.381	-4.406	0.025
100	33	-4.343	-4.540	0.197
100	34	-4.172	-4.406	0.234
100	35	-4.153	-4.349	0.196
100	36	-4.267	-4.521	0.254
100	37	-4.324	-4.406	0.082
100	38	-4.343	-4.616	0.273
100	39	-4.039	-4.158	0.119
100	41	-4.134	-4.387	0.253
100	42	-4.058	-4.253	0.195
100	43	-4.058	-4.330	0.272
100	44	-4.134	-4.349	0.215
	Max	-4.039	-4.158	0.273
	Average	-4.241	-4.372	0.131
	Min	-4.534	-4.616	-0.214
	Std Dev	0.121	0.119	0.123

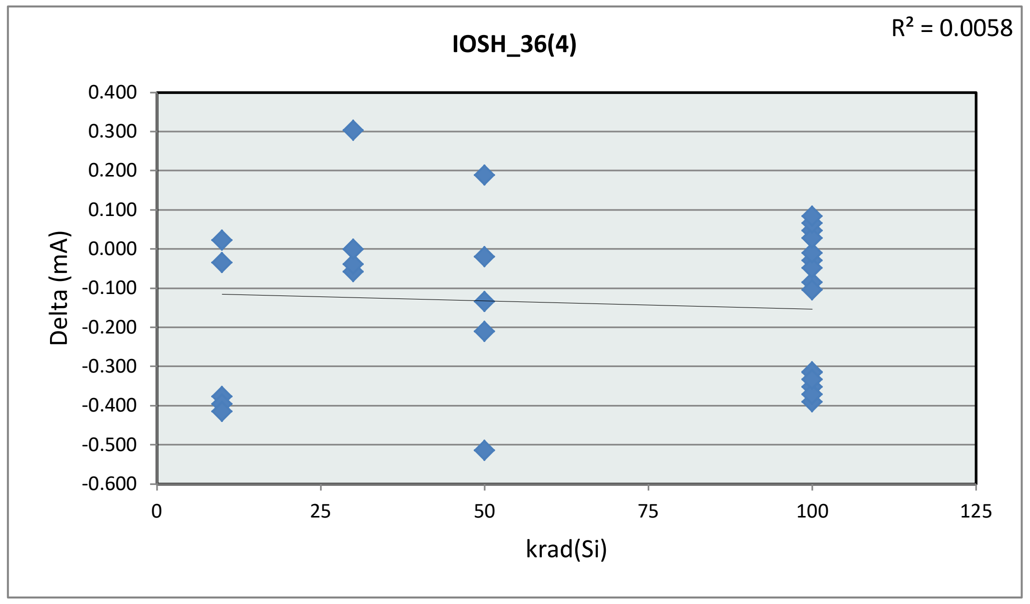


	IOSH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.451	-4.388	-4.407	-4.616
Average	-4.356	-4.296	-4.312	-4.406
Max	-4.184	-4.254	-4.159	-4.158
UL	8.000	8.000	8.000	8.000

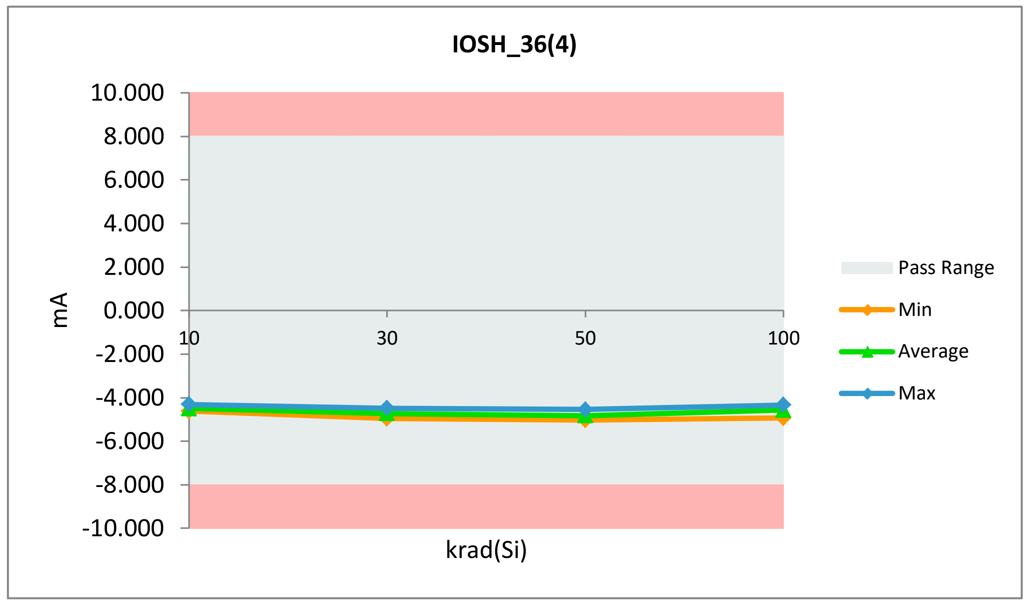


HDR Biased TID Report
SN55LVCP22A-SP

		IOSH_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.838	-4.461	-0.377
10	2	-4.914	-4.518	-0.396
10	3	-4.724	-4.309	-0.415
10	4	-4.591	-4.556	-0.035
10	5	-4.591	-4.613	0.022
30	1	-4.524	-4.523	-0.001
30	2	-4.961	-4.903	-0.058
30	3	-4.657	-4.960	0.303
30	4	-4.790	-4.751	-0.039
30	5	-4.486	-4.485	-0.001
50	11	-5.056	-4.542	-0.514
50	12	-4.847	-5.036	0.189
50	13	-4.999	-4.865	-0.134
50	14	-5.056	-5.036	-0.020
50	15	-4.866	-4.656	-0.210
100	22	-4.781	-4.428	-0.353
100	23	-5.047	-4.942	-0.105
100	24	-4.876	-4.523	-0.353
100	25	-4.515	-4.561	0.046
100	26	-5.028	-4.695	-0.333
100	27	-4.686	-4.657	-0.029
100	28	-4.990	-4.600	-0.390
100	29	-4.781	-4.695	-0.086
100	30	-4.401	-4.428	0.027
100	31	-4.838	-4.733	-0.105
100	32	-4.895	-4.523	-0.372
100	33	-5.028	-4.714	-0.314
100	34	-4.914	-4.542	-0.372
100	35	-4.515	-4.466	-0.049
100	36	-4.534	-4.523	-0.011
100	37	-4.933	-4.619	-0.314
100	38	-4.629	-4.676	0.047
100	39	-4.648	-4.333	-0.315
100	41	-4.363	-4.390	0.027
100	42	-4.781	-4.447	-0.334
100	43	-4.344	-4.409	0.065
100	44	-4.401	-4.485	0.084
	Max	-4.344	-4.309	0.303
	Average	-4.752	-4.611	-0.141
	Min	-5.056	-5.036	-0.514
	Std Dev	0.216	0.189	0.200

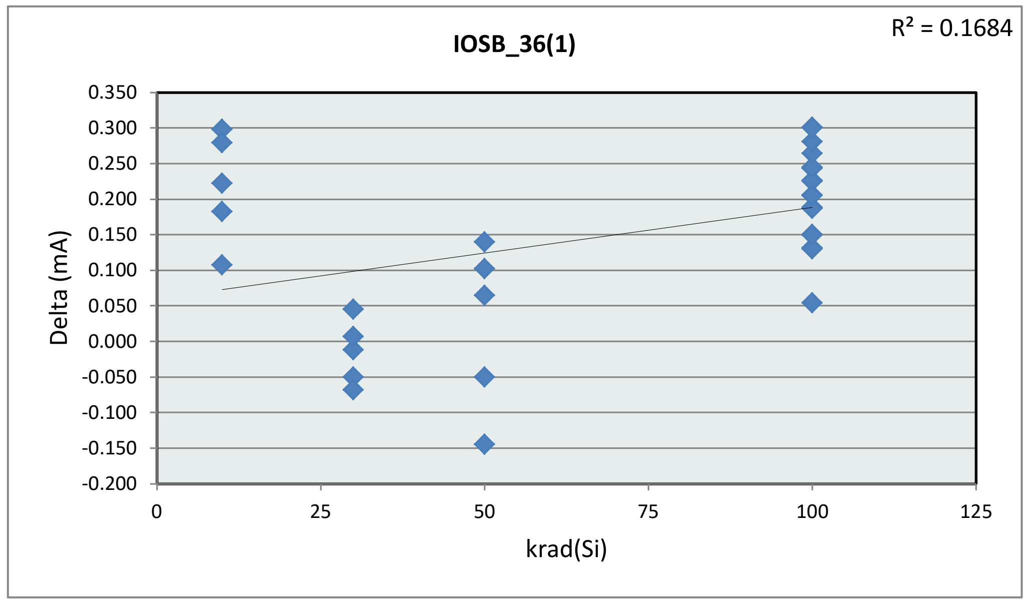


	IOSH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.613	-4.960	-5.036	-4.942
Average	-4.491	-4.724	-4.827	-4.563
Max	-4.309	-4.485	-4.542	-4.333
UL	8.000	8.000	8.000	8.000

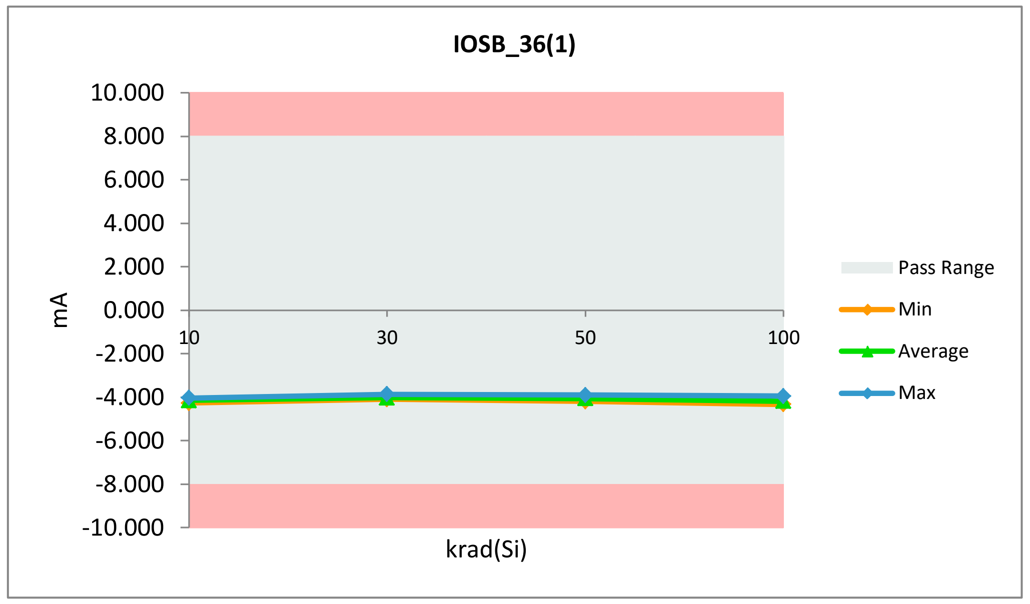


HDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-3.950	-4.057	0.107
10	2	-3.893	-4.191	0.298
10	3	-3.856	-4.038	0.182
10	4	-3.893	-4.172	0.279
10	5	-4.045	-4.267	0.222
30	1	-4.107	-4.095	-0.012
30	2	-3.917	-3.867	-0.050
30	3	-4.145	-4.076	-0.069
30	4	-3.993	-4.038	0.045
30	5	-4.050	-4.057	0.007
50	11	-4.088	-4.152	0.064
50	12	-3.898	-4.038	0.140
50	13	-4.145	-4.000	-0.145
50	14	-3.955	-3.905	-0.050
50	15	-4.088	-4.190	0.102
100	22	-3.874	-4.099	0.225
100	23	-4.007	-4.233	0.226
100	24	-3.950	-4.137	0.187
100	25	-4.007	-4.213	0.206
100	26	-4.159	-4.309	0.150
100	27	-4.083	-4.309	0.226
100	28	-4.140	-4.328	0.188
100	29	-4.045	-4.271	0.226
100	30	-3.837	-4.080	0.243
100	31	-3.969	-4.156	0.187
100	32	-3.874	-4.099	0.225
100	33	-3.893	-4.194	0.301
100	34	-3.988	-4.233	0.245
100	35	-4.121	-4.252	0.131
100	36	-4.007	-4.271	0.264
100	37	-4.102	-4.252	0.150
100	38	-4.007	-4.137	0.130
100	39	-3.893	-3.947	0.054
100	41	-3.950	-4.099	0.149
100	42	-3.818	-4.099	0.281
100	43	-3.856	-4.061	0.205
100	44	-3.856	-4.156	0.300
	Max	-3.818	-3.867	0.301
	Average	-3.985	-4.137	0.152
	Min	-4.159	-4.328	-0.145
	Std Dev	0.102	0.112	0.114



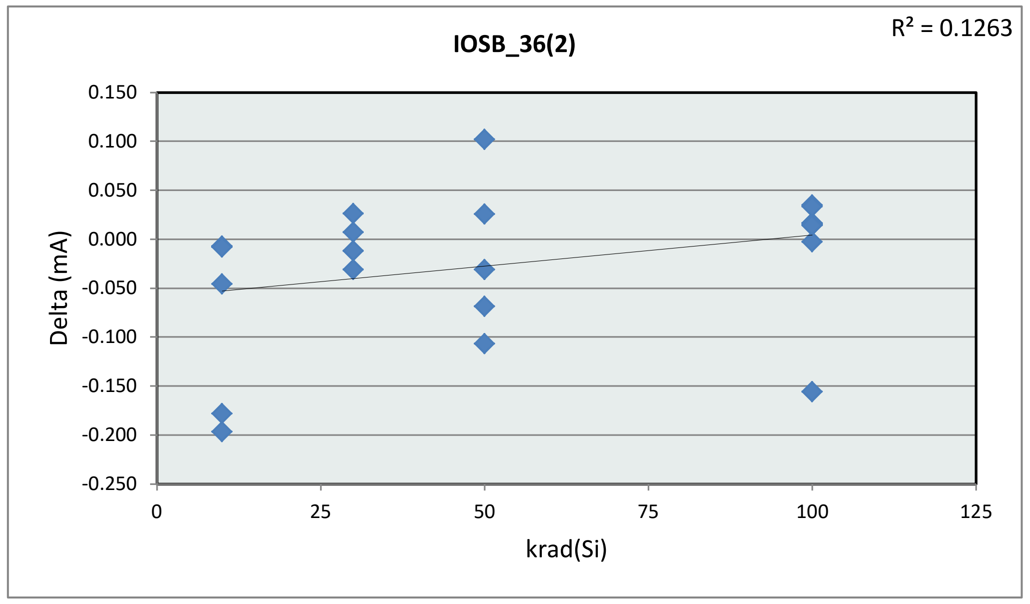
	IOSB_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.267	-4.095	-4.190	-4.328
Average	-4.145	-4.027	-4.057	-4.179
Max	-4.038	-3.867	-3.905	-3.947
UL	8.000	8.000	8.000	8.000



HDR Biased TID Report
SN55LVCP22A-SP

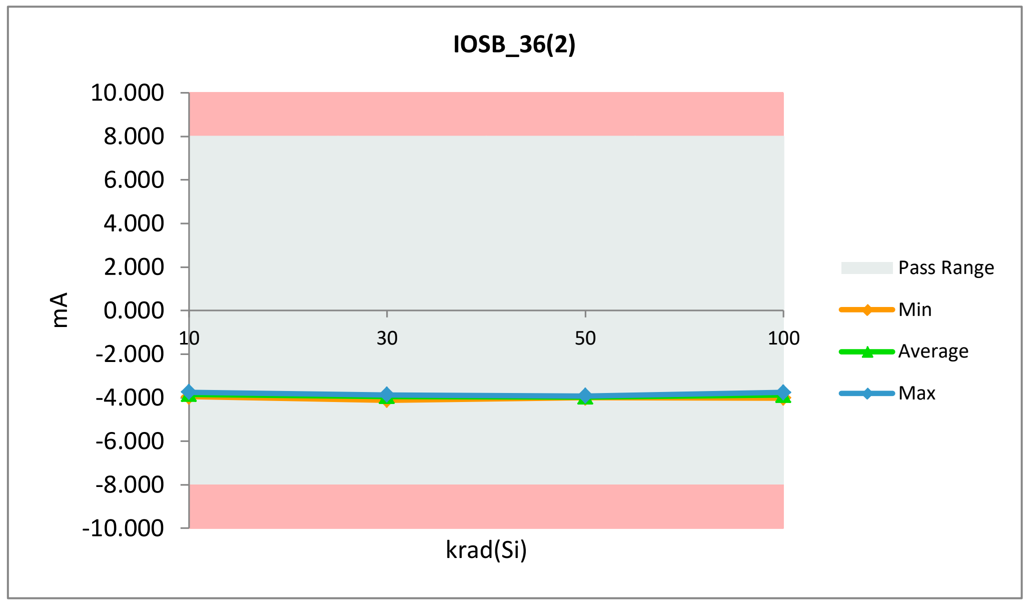
	IOSB_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-3.818	-3.772	-0.046
10	2	-3.893	-3.886	-0.007
10	3	-3.931	-3.753	-0.178
10	4	-3.856	-3.848	-0.008
10	5	-4.159	-3.962	-0.197
30	1	-3.917	-3.924	0.007
30	2	-3.879	-3.867	-0.012
30	3	-4.088	-4.114	0.026
30	4	-3.898	-3.867	-0.031
30	5	-3.936	-3.924	-0.012
50	11	-4.012	-3.981	-0.031
50	12	-3.898	-4.000	0.102
50	13	-3.993	-3.924	-0.069
50	14	-3.898	-3.924	0.026
50	15	-4.107	-4.000	-0.107
100	22	-3.780	-3.794	0.014
100	23	-3.893	-3.927	0.034
100	24	-3.818	-3.832	0.014
100	25	-3.931	-3.947	0.016
100	26	-3.988	-4.004	0.016
100	27	-3.969	-3.985	0.016
100	28	-4.007	-4.023	0.016
100	29	-3.912	-3.947	0.035
100	30	-3.950	-3.794	-0.156
100	31	-3.856	-3.870	0.014
100	32	-3.780	-3.794	0.014
100	33	-3.874	-3.889	0.015
100	34	-3.912	-3.927	0.015
100	35	-3.931	-3.947	0.016
100	36	-3.912	-3.927	0.015
100	37	-3.950	-3.947	-0.003
100	38	-3.837	-3.851	0.014
100	39	-3.761	-3.775	0.014
100	41	-3.950	-3.794	-0.156
100	42	-3.799	-3.813	0.014
100	43	-3.742	-3.756	0.014
100	44	-3.818	-3.851	0.033
	Max	-3.742	-3.753	0.102
	Average	-3.910	-3.896	-0.014
	Min	-4.159	-4.114	-0.197
	Std Dev	0.093	0.086	0.065



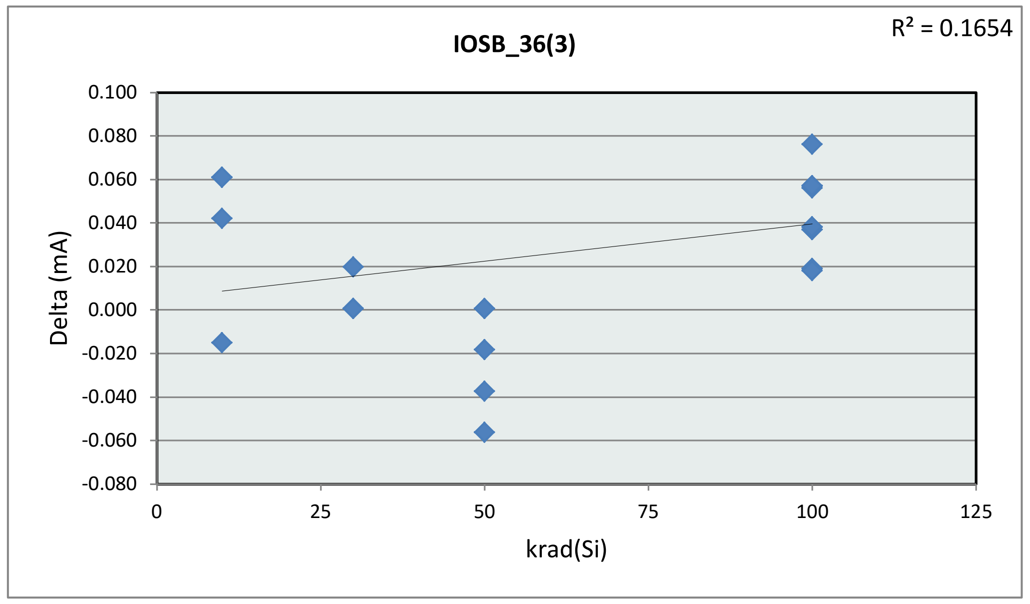
	IOSB_36(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.962	-4.114	-4.000	-4.023
Average	-3.844	-3.939	-3.966	-3.882
Max	-3.753	-3.867	-3.924	-3.756
UL	8.000	8.000	8.000	8.000

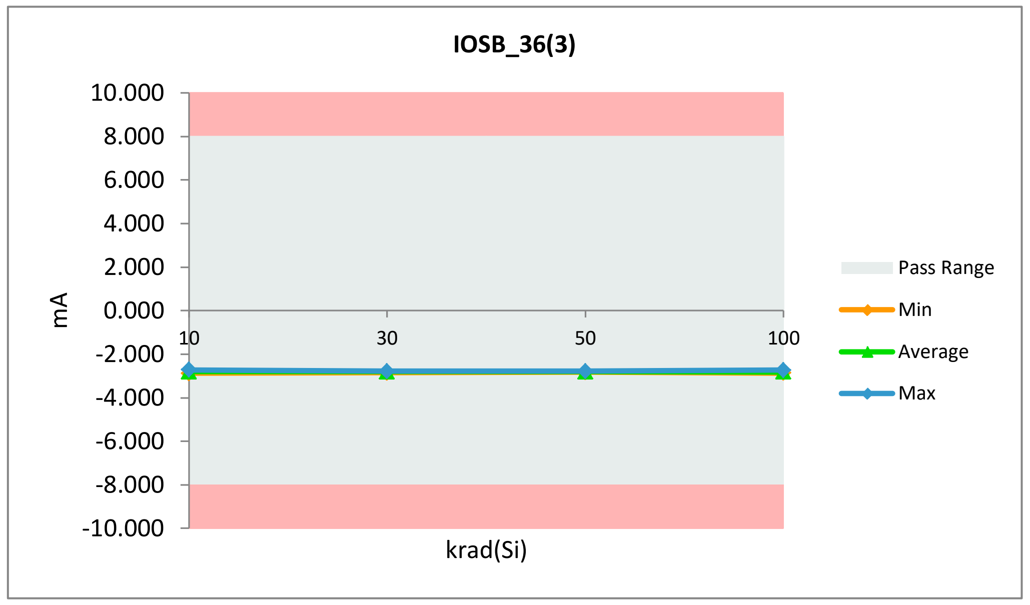


HDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-2.736	-2.797	0.061
10	2	-2.755	-2.797	0.042
10	3	-2.736	-2.721	-0.015
10	4	-2.755	-2.816	0.061
10	5	-2.812	-2.873	0.061
30	1	-2.813	-2.814	0.001
30	2	-2.794	-2.795	0.001
30	3	-2.851	-2.852	0.001
30	4	-2.756	-2.776	0.020
30	5	-2.813	-2.814	0.001
50	11	-2.832	-2.776	-0.056
50	12	-2.813	-2.814	0.001
50	13	-2.832	-2.795	-0.037
50	14	-2.794	-2.776	-0.018
50	15	-2.832	-2.833	0.001
100	22	-2.755	-2.812	0.057
100	23	-2.831	-2.850	0.019
100	24	-2.717	-2.773	0.056
100	25	-2.850	-2.869	0.019
100	26	-2.793	-2.850	0.057
100	27	-2.831	-2.869	0.038
100	28	-2.812	-2.869	0.057
100	29	-2.736	-2.773	0.037
100	30	-2.736	-2.793	0.057
100	31	-2.736	-2.754	0.018
100	32	-2.755	-2.793	0.038
100	33	-2.755	-2.812	0.057
100	34	-2.812	-2.850	0.038
100	35	-2.793	-2.831	0.038
100	36	-2.812	-2.850	0.038
100	37	-2.793	-2.869	0.076
100	38	-2.755	-2.812	0.057
100	39	-2.698	-2.735	0.037
100	41	-2.755	-2.812	0.057
100	42	-2.755	-2.812	0.057
100	43	-2.717	-2.754	0.037
100	44	-2.755	-2.793	0.038
	Max	-2.698	-2.721	0.076
	Average	-2.781	-2.810	0.030
	Min	-2.851	-2.873	-0.056
	Std Dev	0.042	0.039	0.031



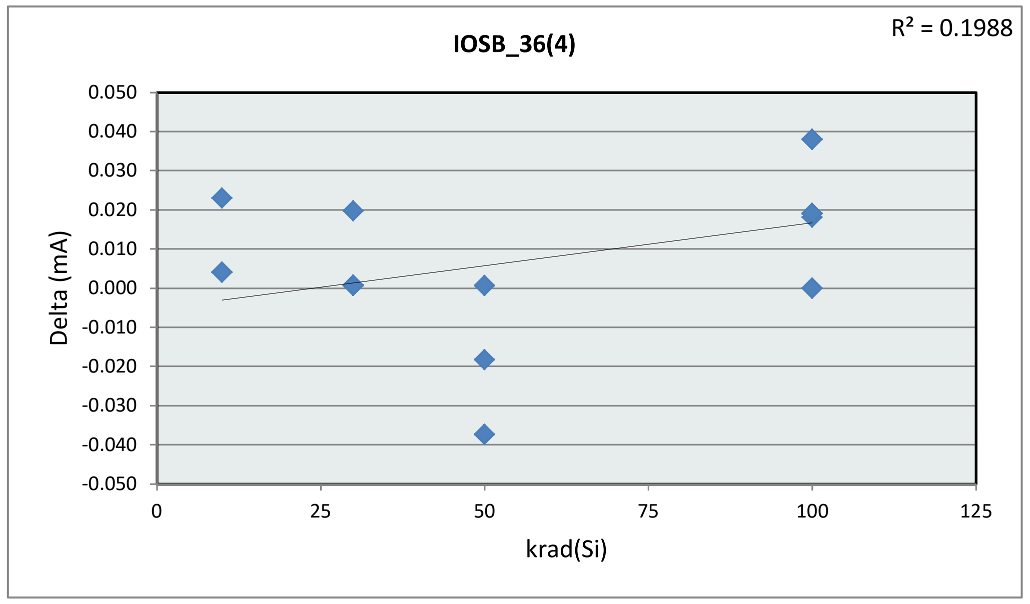
	IOSB_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.873	-2.852	-2.833	-2.869
Average	-2.801	-2.810	-2.799	-2.815
Max	-2.721	-2.776	-2.776	-2.735
UL	8.000	8.000	8.000	8.000



HDR Biased TID Report
SN55LVCP22A-SP

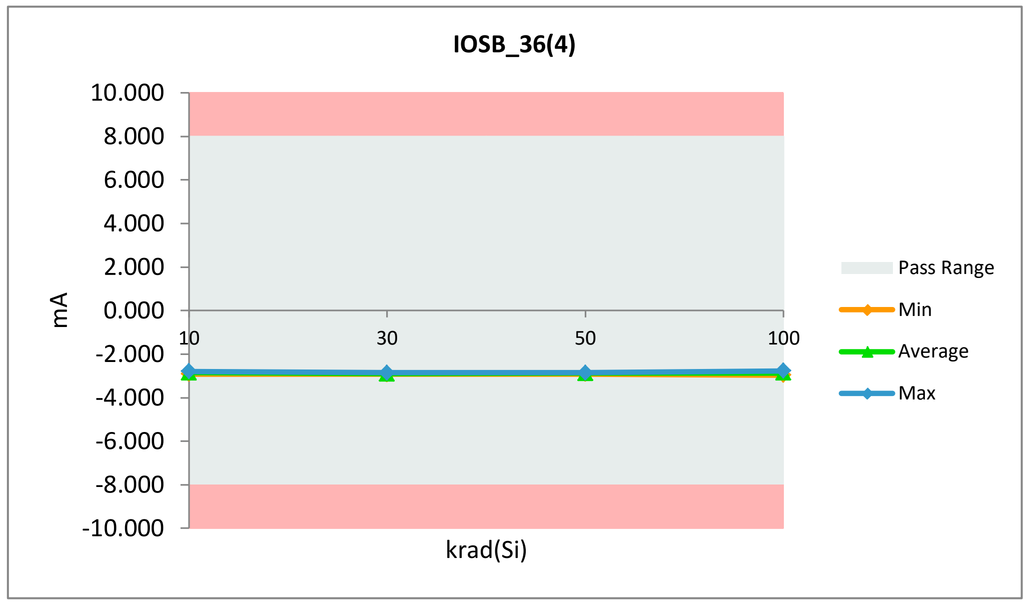
	IOSB_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-2.831	-2.854	0.023
10	2	-2.850	-2.854	0.004
10	3	-2.793	-2.797	0.004
10	4	-2.850	-2.854	0.004
10	5	-2.907	-2.911	0.004
30	1	-2.908	-2.909	0.001
30	2	-2.889	-2.890	0.001
30	3	-2.927	-2.928	0.001
30	4	-2.851	-2.852	0.001
30	5	-2.908	-2.928	0.020
50	11	-2.889	-2.852	-0.037
50	12	-2.889	-2.890	0.001
50	13	-2.908	-2.890	-0.018
50	14	-2.889	-2.852	-0.037
50	15	-2.908	-2.909	0.001
100	22	-2.812	-2.831	0.019
100	23	-2.888	-2.926	0.038
100	24	-2.812	-2.812	0.000
100	25	-2.926	-2.964	0.038
100	26	-2.869	-2.888	0.019
100	27	-2.926	-2.964	0.038
100	28	-2.907	-2.926	0.019
100	29	-2.793	-2.831	0.038
100	30	-2.812	-2.850	0.038
100	31	-2.812	-2.812	0.000
100	32	-2.831	-2.850	0.019
100	33	-2.812	-2.831	0.019
100	34	-2.907	-2.926	0.019
100	35	-2.850	-2.869	0.019
100	36	-2.888	-2.907	0.019
100	37	-2.888	-2.907	0.019
100	38	-2.812	-2.831	0.019
100	39	-2.755	-2.773	0.018
100	41	-2.850	-2.850	0.000
100	42	-2.850	-2.850	0.000
100	43	-2.793	-2.812	0.019
100	44	-2.831	-2.831	0.000
	Max	-2.755	-2.773	0.038
	Average	-2.860	-2.871	0.010
	Min	-2.927	-2.964	-0.037
	Std Dev	0.046	0.047	0.018



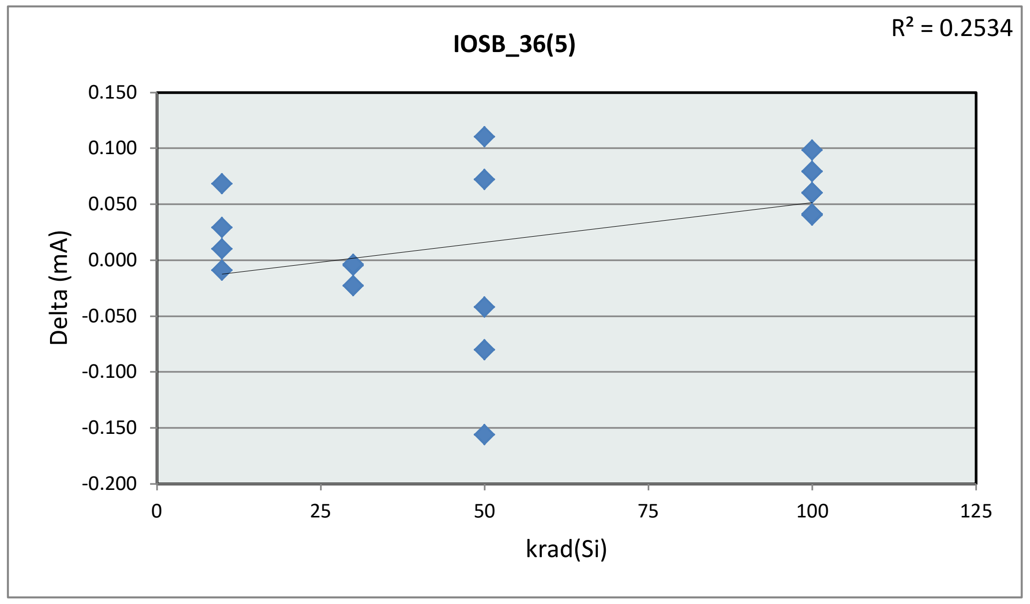
	IOSB_36(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.911	-2.928	-2.909	-2.964
Average	-2.854	-2.901	-2.879	-2.866
Max	-2.797	-2.852	-2.852	-2.773
UL	8.000	8.000	8.000	8.000

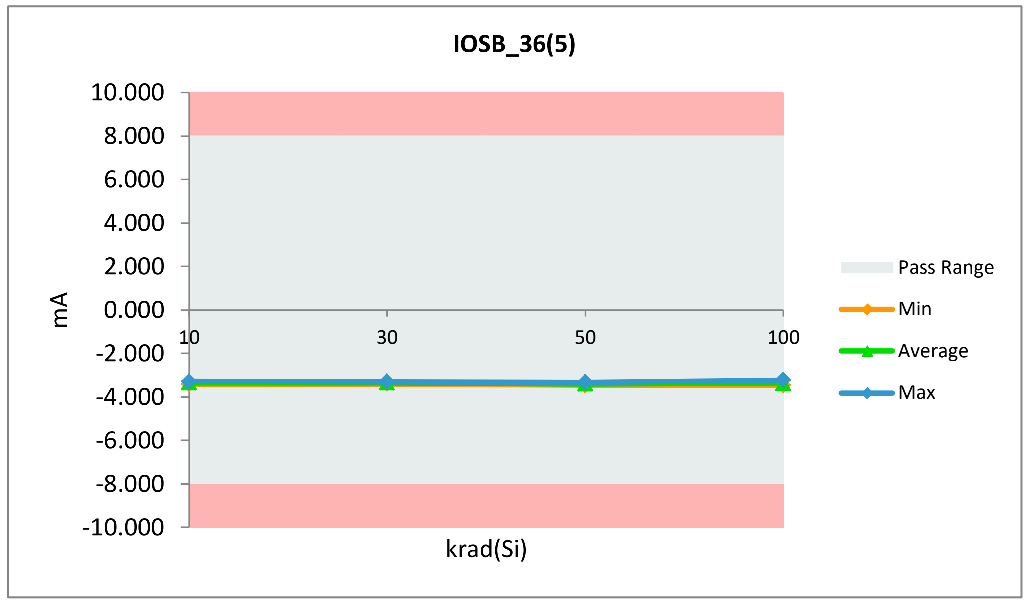


HDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-3.354	-3.364	0.010
10	2	-3.335	-3.326	-0.009
10	3	-3.220	-3.288	0.068
10	4	-3.392	-3.421	0.029
10	5	-3.354	-3.345	-0.009
30	1	-3.307	-3.302	-0.005
30	2	-3.402	-3.379	-0.023
30	3	-3.421	-3.398	-0.023
30	4	-3.326	-3.322	-0.004
30	5	-3.326	-3.322	-0.004
50	11	-3.478	-3.322	-0.156
50	12	-3.345	-3.455	0.110
50	13	-3.421	-3.341	-0.080
50	14	-3.497	-3.455	-0.042
50	15	-3.364	-3.436	0.072
100	22	-3.258	-3.299	0.041
100	23	-3.411	-3.452	0.041
100	24	-3.316	-3.376	0.060
100	25	-3.296	-3.356	0.060
100	26	-3.392	-3.452	0.060
100	27	-3.373	-3.414	0.041
100	28	-3.354	-3.414	0.060
100	29	-3.239	-3.280	0.041
100	30	-3.296	-3.337	0.041
100	31	-3.277	-3.337	0.060
100	32	-3.335	-3.376	0.041
100	33	-3.430	-3.471	0.041
100	34	-3.316	-3.395	0.079
100	35	-3.316	-3.356	0.040
100	36	-3.316	-3.395	0.079
100	37	-3.316	-3.414	0.098
100	38	-3.373	-3.433	0.060
100	39	-3.182	-3.223	0.041
100	41	-3.239	-3.318	0.079
100	42	-3.239	-3.280	0.041
100	43	-3.201	-3.261	0.060
100	44	-3.316	-3.376	0.060
	Max	-3.182	-3.223	0.110
	Average	-3.333	-3.365	0.031
	Min	-3.497	-3.471	-0.156
	Std Dev	0.073	0.062	0.051

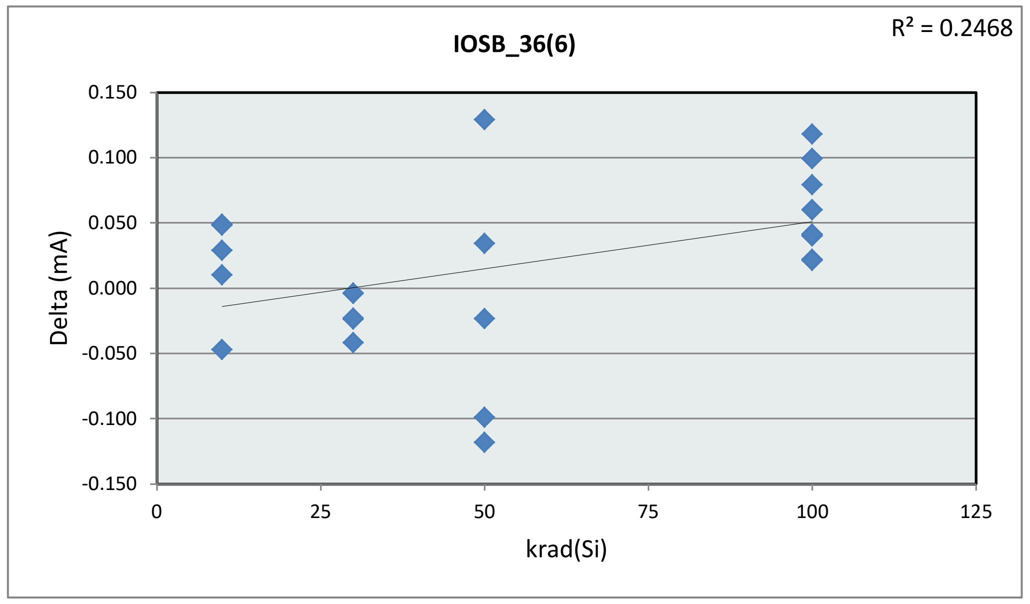


	IOSB_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.421	-3.398	-3.455	-3.471
Average	-3.349	-3.345	-3.402	-3.364
Max	-3.288	-3.302	-3.322	-3.223
UL	8.000	8.000	8.000	8.000

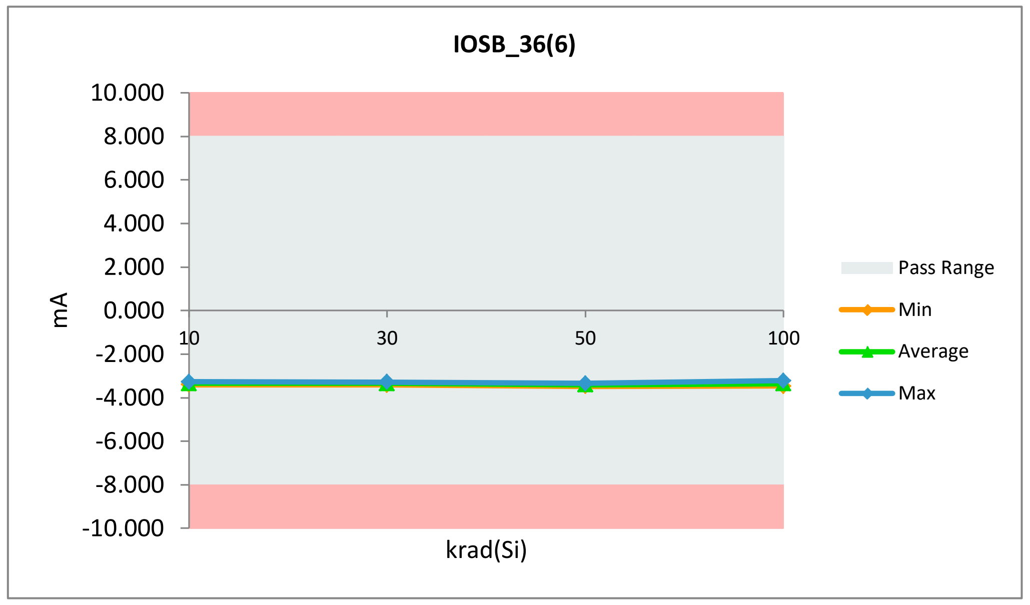


HDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	-3.354	-3.383	0.029
10	2	-3.296	-3.345	0.049
10	3	-3.220	-3.268	0.048
10	4	-3.392	-3.402	0.010
10	5	-3.373	-3.326	-0.047
30	1	-3.307	-3.283	-0.024
30	2	-3.421	-3.398	-0.023
30	3	-3.421	-3.417	-0.004
30	4	-3.326	-3.322	-0.004
30	5	-3.364	-3.322	-0.042
50	11	-3.459	-3.341	-0.118
50	12	-3.345	-3.474	0.129
50	13	-3.440	-3.341	-0.099
50	14	-3.478	-3.455	-0.023
50	15	-3.383	-3.417	0.034
100	22	-3.220	-3.280	0.060
100	23	-3.411	-3.452	0.041
100	24	-3.316	-3.356	0.040
100	25	-3.277	-3.376	0.099
100	26	-3.392	-3.433	0.041
100	27	-3.392	-3.433	0.041
100	28	-3.335	-3.395	0.060
100	29	-3.239	-3.299	0.060
100	30	-3.296	-3.318	0.022
100	31	-3.296	-3.318	0.022
100	32	-3.296	-3.395	0.099
100	33	-3.430	-3.471	0.041
100	34	-3.296	-3.395	0.099
100	35	-3.316	-3.356	0.040
100	36	-3.335	-3.356	0.021
100	37	-3.296	-3.414	0.118
100	38	-3.373	-3.452	0.079
100	39	-3.182	-3.223	0.041
100	41	-3.239	-3.280	0.041
100	42	-3.220	-3.261	0.041
100	43	-3.201	-3.242	0.041
100	44	-3.316	-3.376	0.060
	Max	-3.182	-3.223	0.129
	Average	-3.331	-3.361	0.030
	Min	-3.478	-3.474	-0.118
	Std Dev	0.076	0.067	0.053

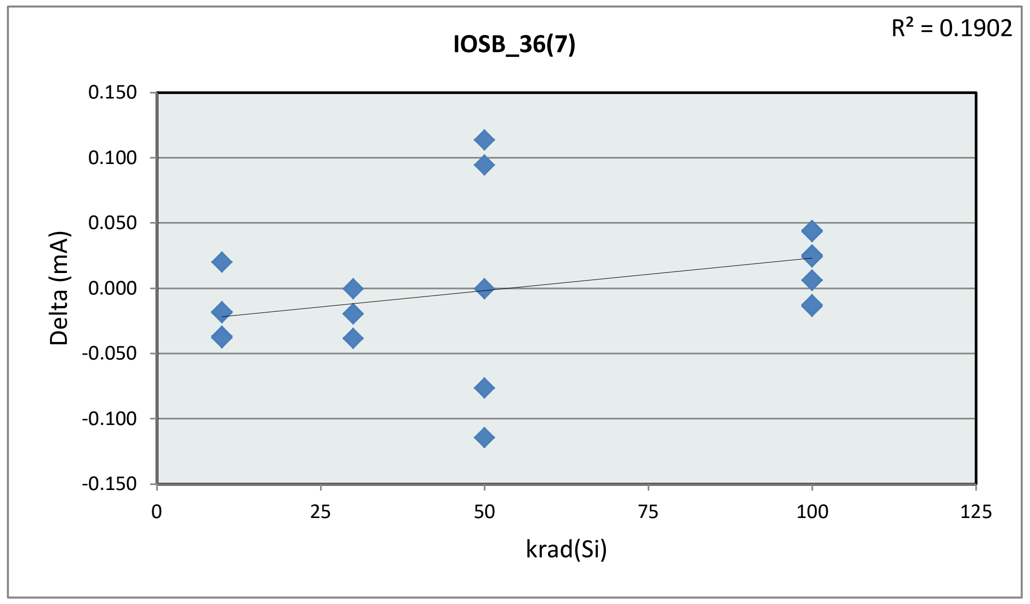


	IOSB_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.402	-3.417	-3.474	-3.471
Average	-3.345	-3.348	-3.406	-3.358
Max	-3.268	-3.283	-3.341	-3.223
UL	8.000	8.000	8.000	8.000

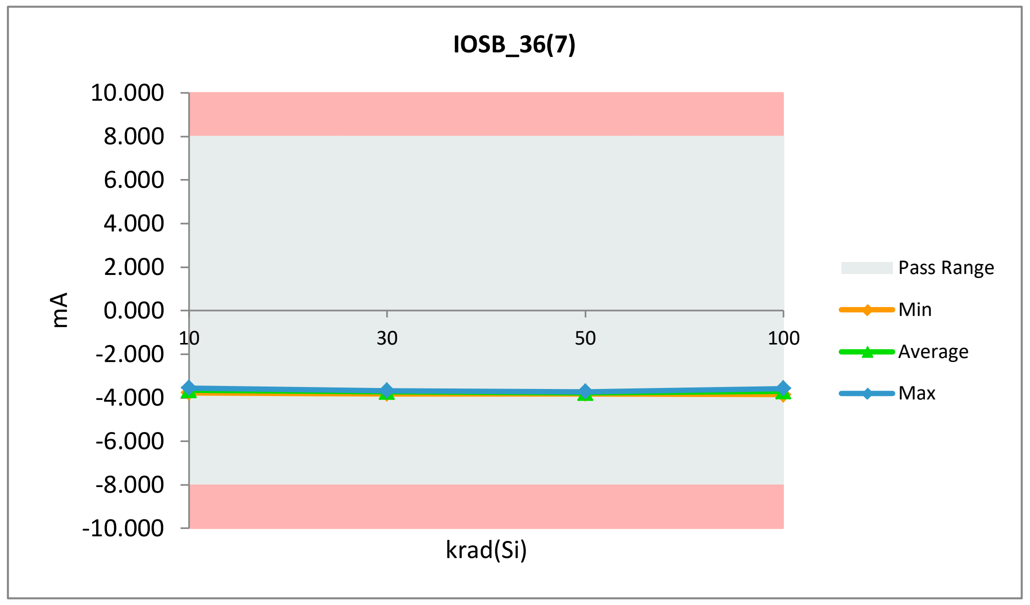


HDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-3.642	-3.623	-0.019
10	2	-3.718	-3.681	-0.037
10	3	-3.585	-3.547	-0.038
10	4	-3.680	-3.700	0.020
10	5	-3.794	-3.776	-0.018
30	1	-3.765	-3.745	-0.020
30	2	-3.727	-3.707	-0.020
30	3	-3.841	-3.821	-0.020
30	4	-3.708	-3.669	-0.039
30	5	-3.727	-3.726	-0.001
50	11	-3.822	-3.745	-0.077
50	12	-3.708	-3.821	0.113
50	13	-3.841	-3.726	-0.115
50	14	-3.803	-3.802	-0.001
50	15	-3.727	-3.821	0.094
100	22	-3.642	-3.628	-0.014
100	23	-3.775	-3.800	0.025
100	24	-3.661	-3.667	0.006
100	25	-3.737	-3.762	0.025
100	26	-3.775	-3.819	0.044
100	27	-3.851	-3.857	0.006
100	28	-3.794	-3.819	0.025
100	29	-3.623	-3.648	0.025
100	30	-3.585	-3.609	0.024
100	31	-3.642	-3.667	0.025
100	32	-3.680	-3.667	-0.013
100	33	-3.737	-3.781	0.044
100	34	-3.737	-3.743	0.006
100	35	-3.680	-3.724	0.044
100	36	-3.718	-3.743	0.025
100	37	-3.737	-3.781	0.044
100	38	-3.794	-3.800	0.006
100	39	-3.528	-3.571	0.043
100	41	-3.585	-3.609	0.024
100	42	-3.585	-3.609	0.024
100	43	-3.604	-3.628	0.024
100	44	-3.604	-3.648	0.044
	Max	-3.528	-3.547	0.113
	Average	-3.707	-3.716	0.009
	Min	-3.851	-3.857	-0.115
	Std Dev	0.084	0.082	0.042



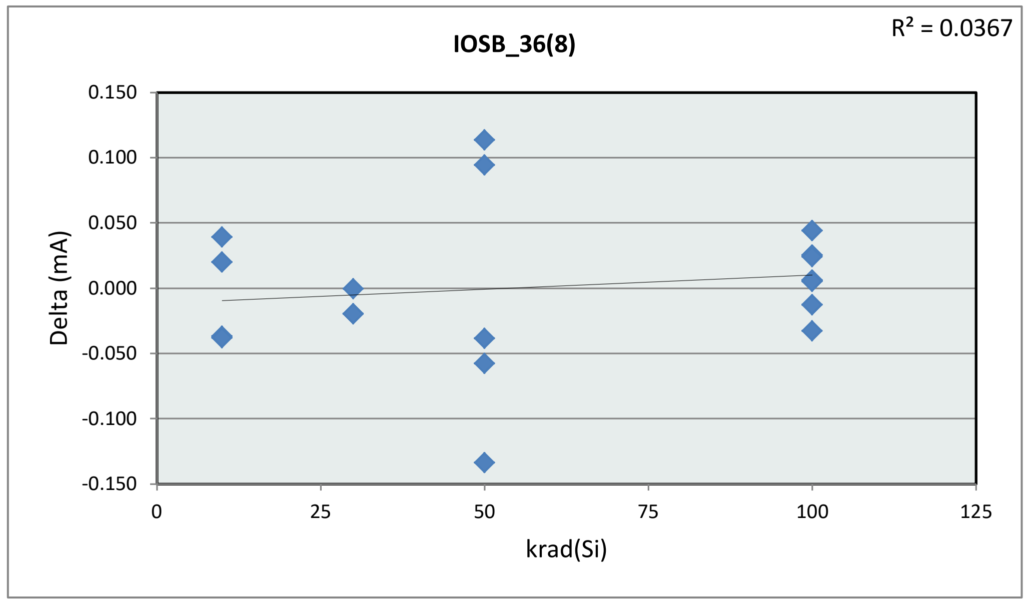
	IOSB_36(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.776	-3.821	-3.821	-3.857
Average	-3.665	-3.734	-3.783	-3.708
Max	-3.547	-3.669	-3.726	-3.571
UL	8.000	8.000	8.000	8.000



HDR Biased TID Report
SN55LVCP22A-SP

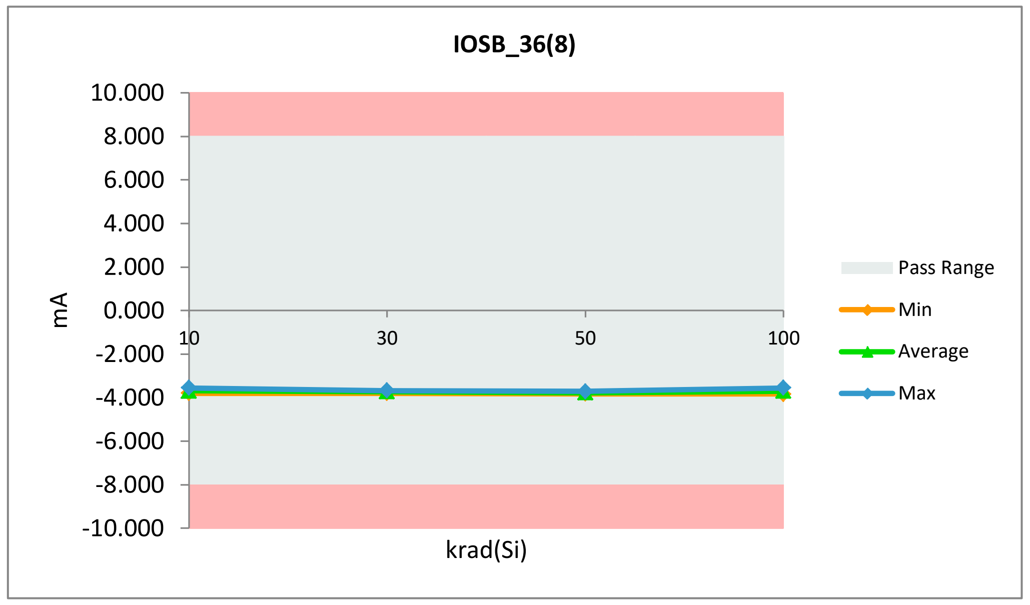
	IOSB_36(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-3.623	-3.662	0.039
10	2	-3.737	-3.700	-0.037
10	3	-3.585	-3.547	-0.038
10	4	-3.699	-3.719	0.020
10	5	-3.775	-3.795	0.020
30	1	-3.746	-3.745	-0.001
30	2	-3.708	-3.688	-0.020
30	3	-3.822	-3.802	-0.020
30	4	-3.689	-3.669	-0.020
30	5	-3.727	-3.707	-0.020
50	11	-3.822	-3.764	-0.058
50	12	-3.689	-3.802	0.113
50	13	-3.841	-3.707	-0.134
50	14	-3.822	-3.783	-0.039
50	15	-3.727	-3.821	0.094
100	22	-3.623	-3.628	0.005
100	23	-3.794	-3.781	-0.013
100	24	-3.661	-3.686	0.025
100	25	-3.756	-3.781	0.025
100	26	-3.794	-3.800	0.006
100	27	-3.832	-3.838	0.006
100	28	-3.813	-3.819	0.006
100	29	-3.623	-3.667	0.044
100	30	-3.642	-3.609	-0.033
100	31	-3.642	-3.648	0.006
100	32	-3.680	-3.686	0.006
100	33	-3.775	-3.800	0.025
100	34	-3.737	-3.724	-0.013
100	35	-3.699	-3.724	0.025
100	36	-3.699	-3.743	0.044
100	37	-3.756	-3.743	-0.013
100	38	-3.794	-3.800	0.006
100	39	-3.528	-3.552	0.024
100	41	-3.604	-3.609	0.005
100	42	-3.604	-3.609	0.005
100	43	-3.604	-3.609	0.005
100	44	-3.604	-3.648	0.044
	Max	-3.528	-3.547	0.113
	Average	-3.710	-3.714	0.004
	Min	-3.841	-3.838	-0.134
	Std Dev	0.083	0.079	0.041



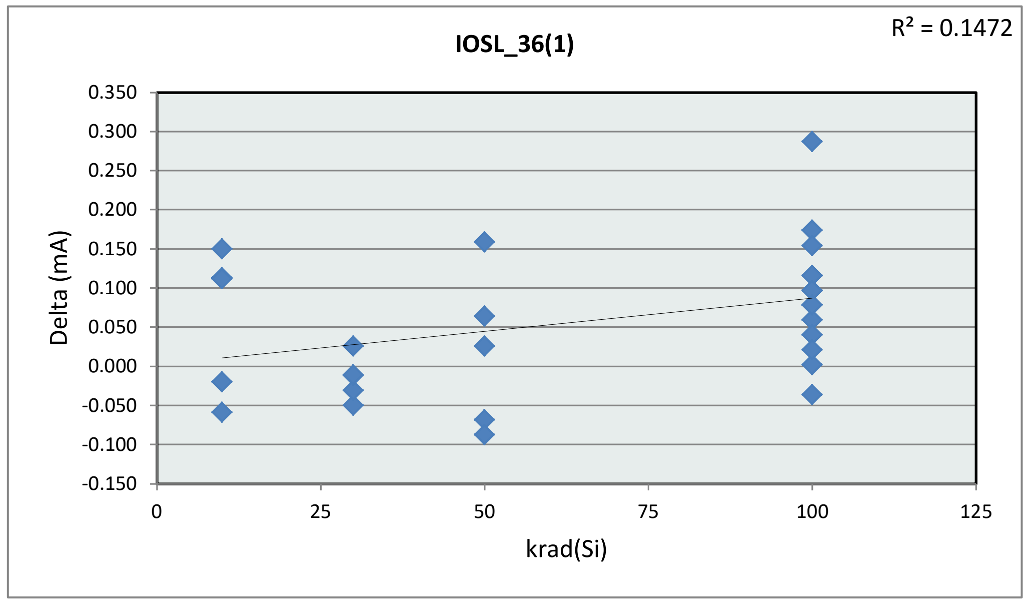
	IOSB_36(8)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.795	-3.802	-3.821	-3.838
Average	-3.685	-3.722	-3.775	-3.705
Max	-3.547	-3.669	-3.707	-3.552
UL	8.000	8.000	8.000	8.000

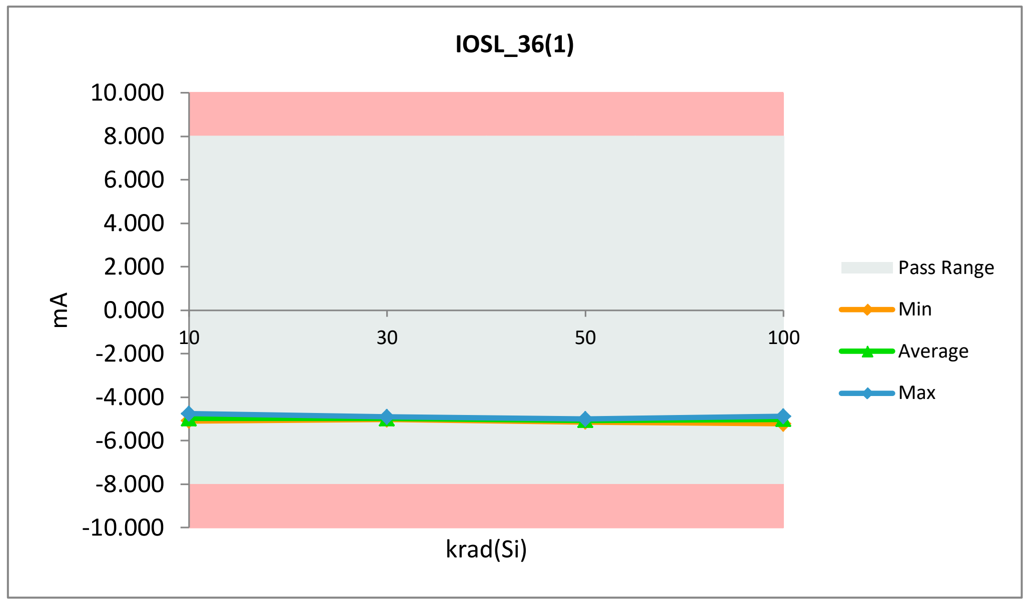


HDR Biased TID Report
SN55LVCP22A-SP

		IOSL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.841	-4.991	0.150
10	2	-4.974	-5.087	0.113
10	3	-4.822	-4.763	-0.059
10	4	-4.898	-5.010	0.112
10	5	-5.069	-5.049	-0.020
30	1	-5.054	-5.004	-0.050
30	2	-4.978	-4.947	-0.031
30	3	-5.035	-5.023	-0.012
30	4	-4.921	-4.910	-0.011
30	5	-4.959	-4.985	0.026
50	11	-5.130	-5.061	-0.069
50	12	-4.978	-5.137	0.159
50	13	-5.092	-5.004	-0.088
50	14	-4.997	-5.023	0.026
50	15	-5.016	-5.080	0.064
100	22	-4.860	-4.900	0.040
100	23	-5.031	-4.995	-0.036
100	24	-4.860	-4.957	0.097
100	25	-5.012	-5.128	0.116
100	26	-5.050	-5.224	0.174
100	27	-5.069	-5.128	0.059
100	28	-5.031	-5.109	0.078
100	29	-4.993	-5.167	0.174
100	30	-4.746	-5.033	0.287
100	31	-4.917	-5.014	0.097
100	32	-4.860	-4.938	0.078
100	33	-4.974	-4.976	0.002
100	34	-4.993	-5.052	0.059
100	35	-4.993	-5.109	0.116
100	36	-4.898	-4.995	0.097
100	37	-5.012	-5.128	0.116
100	38	-4.898	-4.938	0.040
100	39	-4.822	-4.900	0.078
100	41	-4.841	-4.938	0.097
100	42	-4.879	-4.957	0.078
100	43	-4.746	-4.900	0.154
100	44	-4.860	-4.881	0.021
	Max	-4.746	-4.763	0.287
	Average	-4.949	-5.012	0.063
	Min	-5.130	-5.224	-0.088
	Std Dev	0.096	0.094	0.080

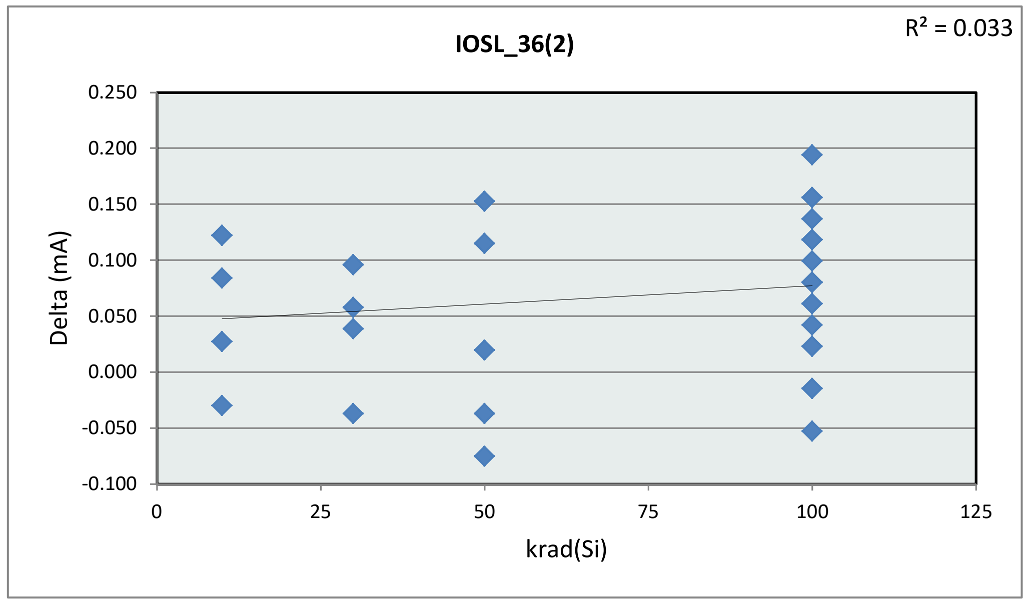


	IOSL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.087	-5.023	-5.137	-5.224
Average	-4.980	-4.974	-5.061	-5.017
Max	-4.763	-4.910	-5.004	-4.881
UL	8.000	8.000	8.000	8.000

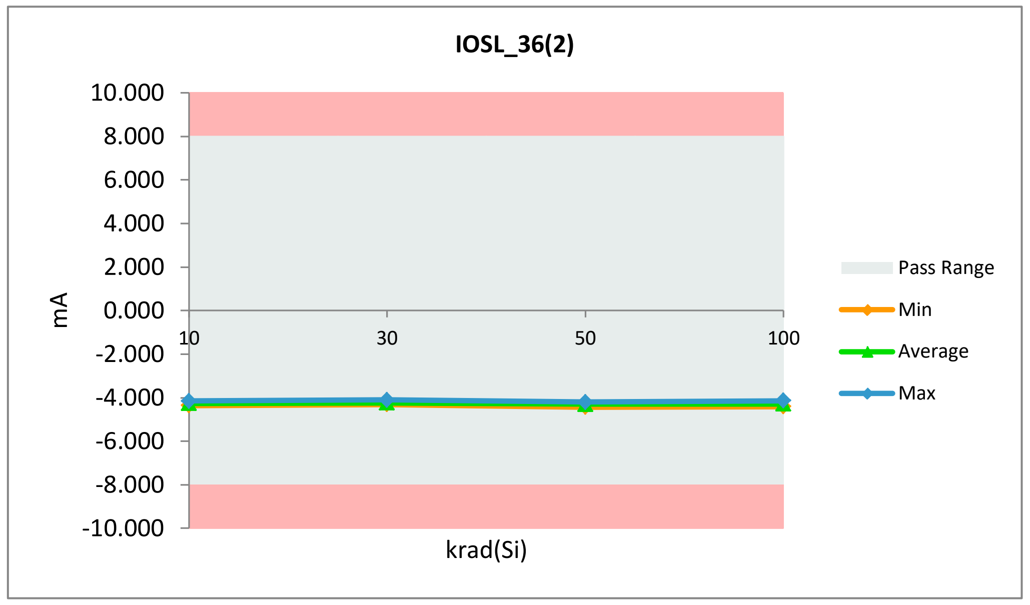


HDR Biased TID Report
SN55LVCP22A-SP

		IOSL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.122	-4.244	0.122
10	2	-4.217	-4.301	0.084
10	3	-4.179	-4.149	-0.030
10	4	-4.160	-4.282	0.122
10	5	-4.331	-4.358	0.027
30	1	-4.180	-4.238	0.058
30	2	-4.199	-4.238	0.039
30	3	-4.199	-4.295	0.096
30	4	-4.142	-4.105	-0.037
30	5	-4.218	-4.314	0.096
50	11	-4.332	-4.257	-0.075
50	12	-4.256	-4.276	0.020
50	13	-4.313	-4.428	0.115
50	14	-4.237	-4.200	-0.037
50	15	-4.180	-4.333	0.153
100	22	-4.160	-4.221	0.061
100	23	-4.388	-4.335	-0.053
100	24	-4.084	-4.202	0.118
100	25	-4.293	-4.373	0.080
100	26	-4.369	-4.392	0.023
100	27	-4.293	-4.373	0.080
100	28	-4.255	-4.411	0.156
100	29	-4.179	-4.278	0.099
100	30	-4.122	-4.259	0.137
100	31	-4.236	-4.221	-0.015
100	32	-4.160	-4.183	0.023
100	33	-4.293	-4.278	-0.015
100	34	-4.293	-4.354	0.061
100	35	-4.198	-4.354	0.156
100	36	-4.179	-4.316	0.137
100	37	-4.236	-4.354	0.118
100	38	-4.179	-4.259	0.080
100	39	-4.065	-4.145	0.080
100	41	-4.198	-4.240	0.042
100	42	-4.179	-4.259	0.080
100	43	-4.084	-4.202	0.118
100	44	-4.141	-4.335	0.194
	Max	-4.065	-4.105	0.194
	Average	-4.212	-4.280	0.068
	Min	-4.388	-4.428	-0.075
	Std Dev	0.079	0.077	0.066

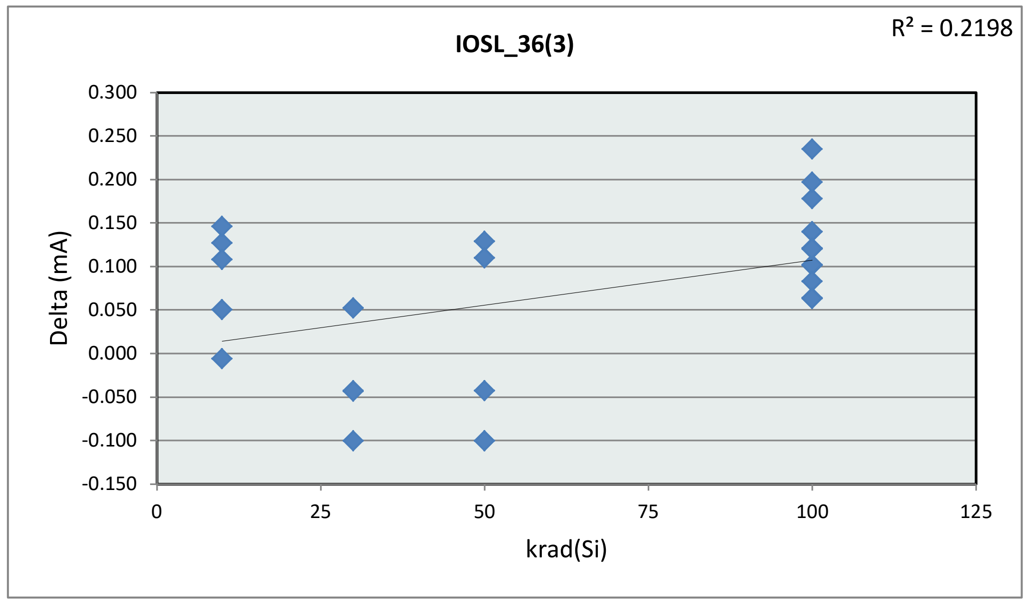


	IOSL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.358	-4.314	-4.428	-4.411
Average	-4.267	-4.238	-4.299	-4.288
Max	-4.149	-4.105	-4.200	-4.145
UL	8.000	8.000	8.000	8.000

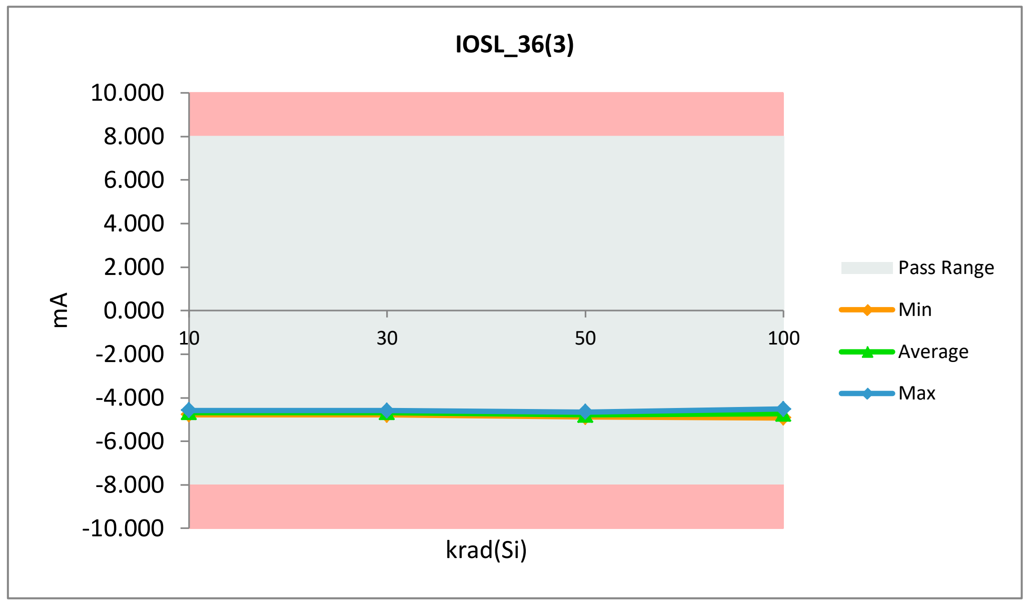


HDR Biased TID Report
SN55LVCP22A-SP

		IOSL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.572	-4.699	0.127
10	2	-4.610	-4.718	0.108
10	3	-4.534	-4.584	0.050
10	4	-4.629	-4.775	0.146
10	5	-4.648	-4.642	-0.006
30	1	-4.640	-4.597	-0.043
30	2	-4.812	-4.711	-0.101
30	3	-4.831	-4.787	-0.044
30	4	-4.621	-4.673	0.052
30	5	-4.602	-4.654	0.052
50	11	-4.812	-4.711	-0.101
50	12	-4.697	-4.826	0.129
50	13	-4.754	-4.654	-0.100
50	14	-4.888	-4.845	-0.043
50	15	-4.773	-4.883	0.110
100	22	-4.534	-4.654	0.120
100	23	-4.781	-4.921	0.140
100	24	-4.610	-4.711	0.101
100	25	-4.572	-4.750	0.178
100	26	-4.648	-4.845	0.197
100	27	-4.781	-4.883	0.102
100	28	-4.743	-4.883	0.140
100	29	-4.515	-4.616	0.101
100	30	-4.572	-4.635	0.063
100	31	-4.591	-4.654	0.063
100	32	-4.629	-4.750	0.121
100	33	-4.781	-4.845	0.064
100	34	-4.591	-4.826	0.235
100	35	-4.572	-4.692	0.120
100	36	-4.686	-4.788	0.102
100	37	-4.686	-4.769	0.083
100	38	-4.762	-4.883	0.121
100	39	-4.458	-4.521	0.063
100	41	-4.534	-4.654	0.120
100	42	-4.458	-4.578	0.120
100	43	-4.496	-4.616	0.120
100	44	-4.629	-4.692	0.063
	Max	-4.458	-4.521	0.235
	Average	-4.650	-4.728	0.078
	Min	-4.888	-4.921	-0.101
	Std Dev	0.111	0.103	0.080

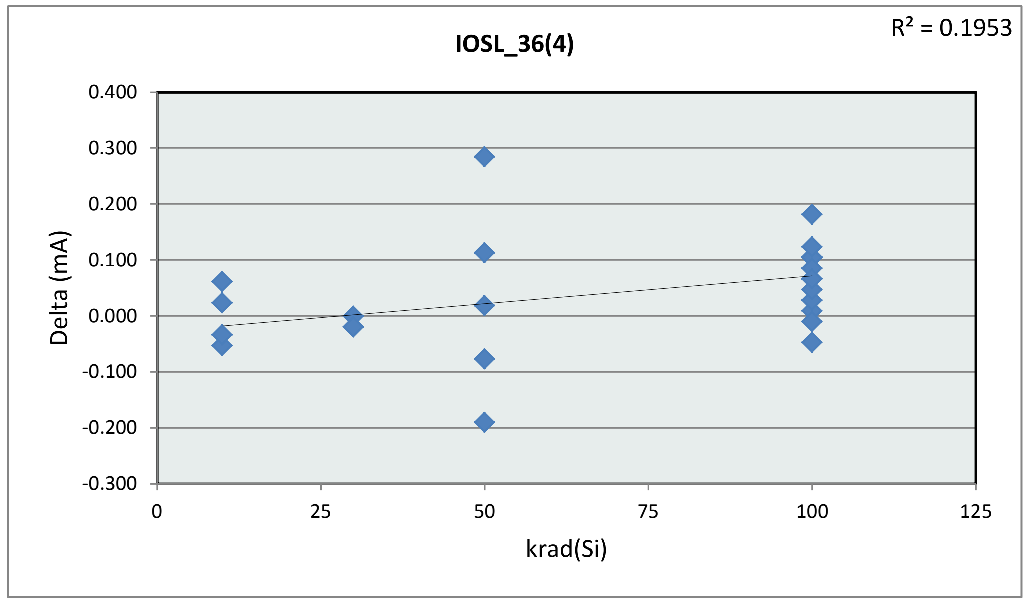


	IOSL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.775	-4.787	-4.883	-4.921
Average	-4.684	-4.684	-4.784	-4.735
Max	-4.584	-4.597	-4.654	-4.521
UL	8.000	8.000	8.000	8.000

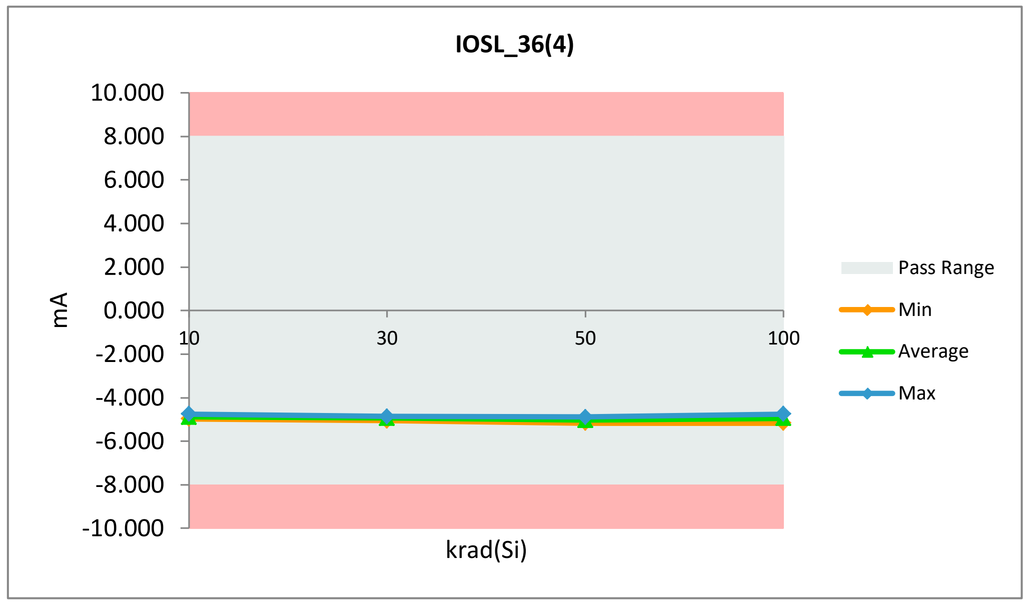


HDR Biased TID Report
SN55LVCP22A-SP

		IOSL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.876	-4.823	-0.053
10	2	-4.914	-4.937	0.023
10	3	-4.686	-4.747	0.061
10	4	-4.990	-4.956	-0.034
10	5	-5.009	-4.975	-0.034
30	1	-4.942	-4.922	-0.020
30	2	-4.942	-4.941	-0.001
30	3	-5.075	-5.055	-0.020
30	4	-4.885	-4.865	-0.020
30	5	-4.923	-4.903	-0.020
50	11	-5.037	-4.960	-0.077
50	12	-4.885	-5.169	0.284
50	13	-5.075	-4.884	-0.191
50	14	-5.056	-5.074	0.018
50	15	-4.942	-5.055	0.113
100	22	-4.819	-4.847	0.028
100	23	-5.028	-5.133	0.105
100	24	-4.952	-4.961	0.009
100	25	-4.914	-5.018	0.104
100	26	-4.971	-5.076	0.105
100	27	-5.009	-4.999	-0.010
100	28	-4.990	-4.942	-0.048
100	29	-4.781	-4.847	0.066
100	30	-4.762	-4.828	0.066
100	31	-4.819	-4.923	0.104
100	32	-4.857	-4.942	0.085
100	33	-4.990	-5.171	0.181
100	34	-4.933	-4.999	0.066
100	35	-4.876	-4.942	0.066
100	36	-4.857	-4.885	0.028
100	37	-4.933	-4.980	0.047
100	38	-4.990	-5.095	0.105
100	39	-4.648	-4.752	0.104
100	41	-4.743	-4.847	0.104
100	42	-4.724	-4.847	0.123
100	43	-4.743	-4.828	0.085
100	44	-4.800	-4.866	0.066
	Max	-4.648	-4.747	0.284
	Average	-4.902	-4.946	0.044
	Min	-5.075	-5.171	-0.191
	Std Dev	0.111	0.107	0.082

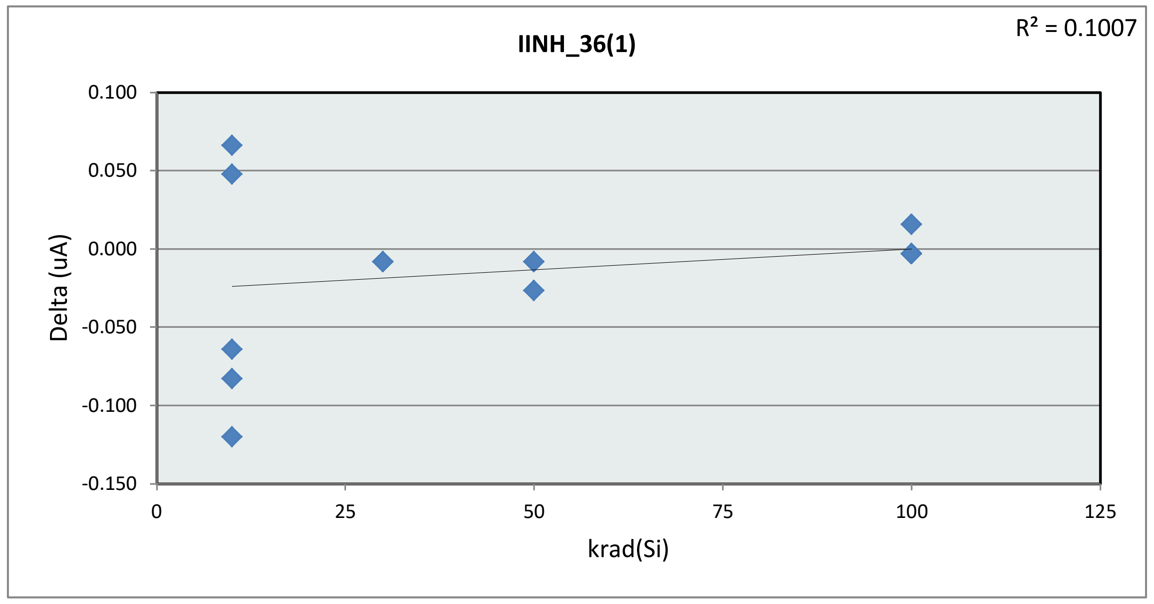


	IOSL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.975	-5.055	-5.169	-5.171
Average	-4.888	-4.937	-5.028	-4.942
Max	-4.747	-4.865	-4.884	-4.752
UL	8.000	8.000	8.000	8.000

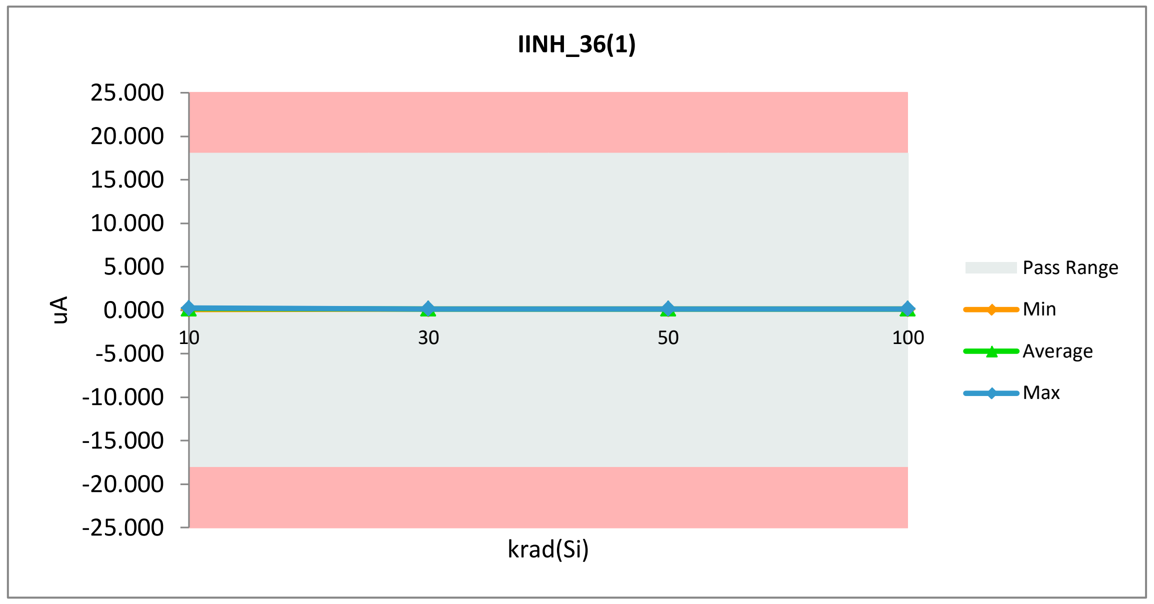


HDR Biased TID Report
SN55LVCP22A-SP

		IINH_36(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	0.130	0.250	-0.120
10	2	0.148	0.082	0.066
10	3	0.148	0.212	-0.064
10	4	0.130	0.082	0.048
10	5	0.148	0.231	-0.083
30	1	0.143	0.151	-0.008
30	2	0.106	0.114	-0.008
30	3	0.143	0.151	-0.008
30	4	0.143	0.151	-0.008
30	5	0.125	0.133	-0.008
50	11	0.125	0.151	-0.027
50	12	0.125	0.133	-0.008
50	13	0.143	0.151	-0.008
50	14	0.143	0.151	-0.008
50	15	0.125	0.151	-0.027
100	22	0.130	0.133	-0.003
100	23	0.130	0.133	-0.003
100	24	0.148	0.151	-0.003
100	25	0.148	0.151	-0.003
100	26	0.148	0.151	-0.003
100	27	0.148	0.151	-0.003
100	28	0.148	0.151	-0.003
100	29	0.148	0.151	-0.003
100	30	0.148	0.151	-0.003
100	31	0.148	0.133	0.016
100	32	0.148	0.133	0.016
100	33	0.148	0.133	0.016
100	34	0.148	0.151	-0.003
100	35	0.148	0.151	-0.003
100	36	0.148	0.151	-0.003
100	37	0.148	0.151	-0.003
100	38	0.148	0.151	-0.003
100	39	0.130	0.133	-0.003
100	41	0.148	0.151	-0.003
100	42	0.148	0.151	-0.003
100	43	0.148	0.151	-0.003
100	44	0.148	0.151	-0.003
	Max	0.148	0.250	0.066
	Average	0.141	0.149	-0.008
	Min	0.106	0.082	-0.120
	Std Dev	0.011	0.030	0.030



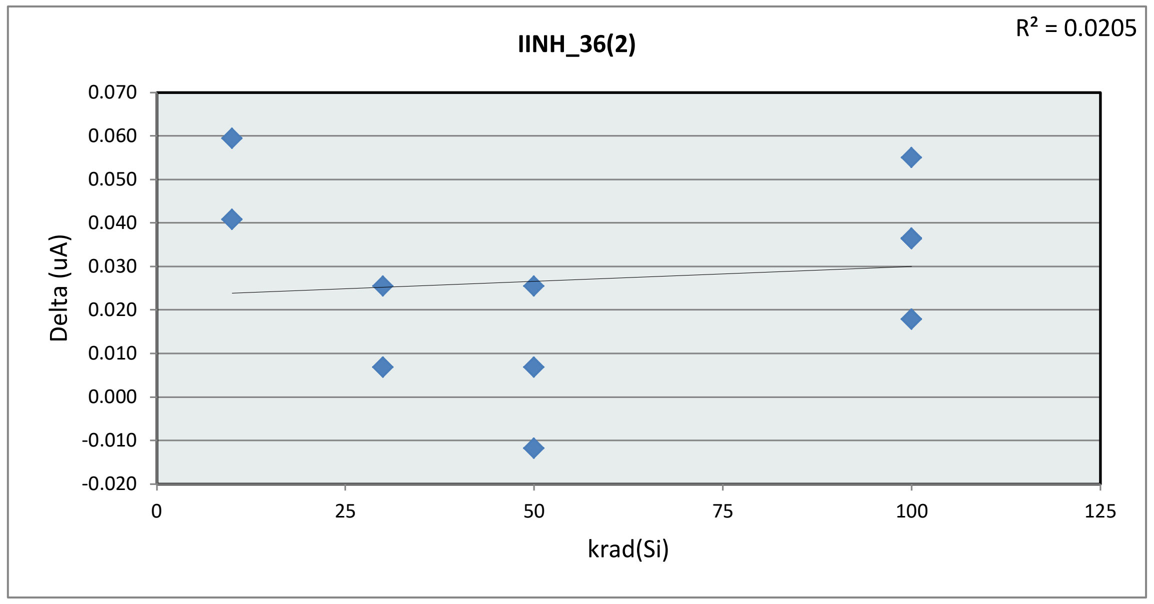
	IINH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.082	0.114	0.133	0.133
Average	0.171	0.140	0.148	0.146
Max	0.250	0.151	0.151	0.151
UL	18.000	18.000	18.000	18.000



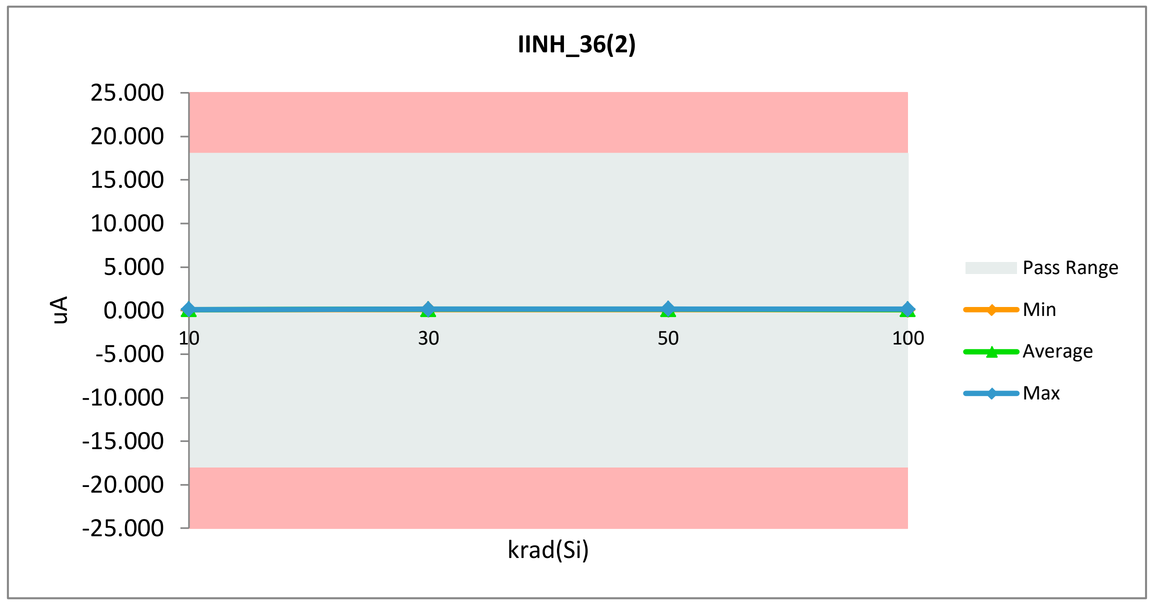
HDR Biased TID Report
SN55LVCP22A-SP

	IINH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.156	0.097	0.059
10	2	0.175	0.116	0.059
10	3	0.156	0.116	0.041
10	4	0.156	0.116	0.041
10	5	0.138	0.097	0.041
30	1	0.163	0.138	0.025
30	2	0.126	0.119	0.007
30	3	0.163	0.157	0.007
30	4	0.163	0.157	0.007
30	5	0.145	0.138	0.007
50	11	0.163	0.157	0.007
50	12	0.163	0.138	0.025
50	13	0.163	0.157	0.007
50	14	0.145	0.157	-0.012
50	15	0.163	0.175	-0.012
100	22	0.156	0.120	0.036
100	23	0.156	0.120	0.036
100	24	0.156	0.138	0.018
100	25	0.156	0.138	0.018
100	26	0.156	0.120	0.036
100	27	0.175	0.138	0.036
100	28	0.156	0.120	0.036
100	29	0.156	0.138	0.018
100	30	0.156	0.120	0.036
100	31	0.138	0.101	0.036
100	32	0.156	0.120	0.036
100	33	0.138	0.101	0.036
100	34	0.138	0.120	0.018
100	35	0.156	0.138	0.018
100	36	0.156	0.120	0.036
100	37	0.156	0.120	0.036
100	38	0.156	0.120	0.036
100	39	0.138	0.101	0.036
100	41	0.156	0.120	0.036
100	42	0.156	0.120	0.036
100	43	0.156	0.120	0.036
100	44	0.175	0.120	0.055
	Max	0.175	0.175	0.059
	Average	0.155	0.127	0.028
	Min	0.126	0.097	-0.012
	Std Dev	0.011	0.019	0.017

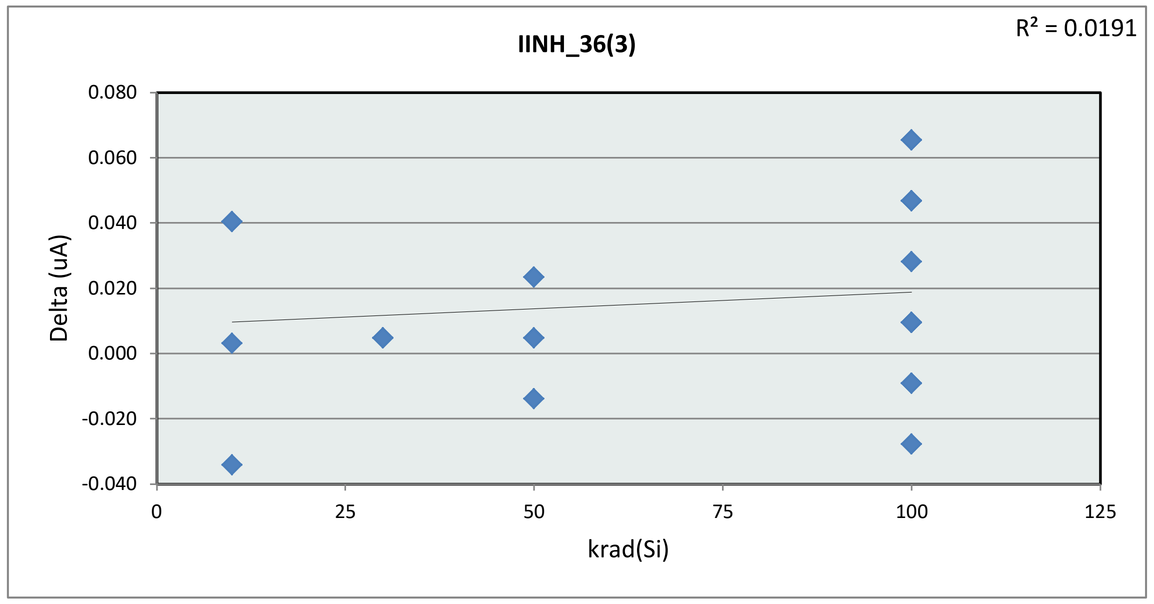


	IINH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.097	0.119	0.138	0.101
Average	0.108	0.142	0.157	0.122
Max	0.116	0.157	0.175	0.138
UL	18.000	18.000	18.000	18.000

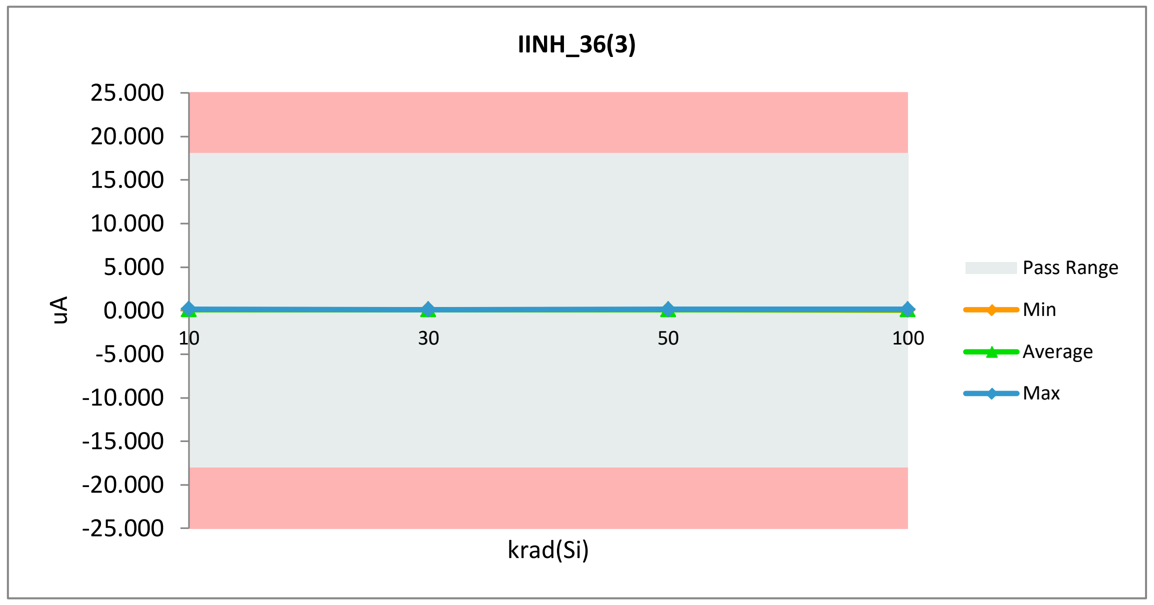


HDR Biased TID Report
SN55LVCP22A-SP

		IINH_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.138	0.098	0.040
10	2	0.157	0.153	0.003
10	3	0.138	0.172	-0.034
10	4	0.138	0.098	0.040
10	5	0.138	0.098	0.040
30	1	0.138	0.133	0.005
30	2	0.119	0.115	0.005
30	3	0.138	0.133	0.005
30	4	0.138	0.133	0.005
30	5	0.119	0.115	0.005
50	11	0.138	0.133	0.005
50	12	0.138	0.133	0.005
50	13	0.157	0.133	0.023
50	14	0.138	0.115	0.023
50	15	0.138	0.152	-0.014
100	22	0.119	0.110	0.009
100	23	0.138	0.091	0.047
100	24	0.138	0.110	0.028
100	25	0.157	0.166	-0.009
100	26	0.138	0.166	-0.028
100	27	0.157	0.110	0.047
100	28	0.138	0.073	0.065
100	29	0.138	0.073	0.065
100	30	0.138	0.128	0.009
100	31	0.157	0.110	0.047
100	32	0.138	0.128	0.009
100	33	0.138	0.147	-0.009
100	34	0.138	0.073	0.065
100	35	0.138	0.091	0.047
100	36	0.138	0.147	-0.009
100	37	0.138	0.091	0.047
100	38	0.138	0.128	0.009
100	39	0.138	0.128	0.009
100	41	0.138	0.166	-0.028
100	42	0.138	0.128	0.009
100	43	0.138	0.128	0.009
100	44	0.138	0.147	-0.009
	Max	0.157	0.172	0.065
	Average	0.139	0.123	0.016
	Min	0.119	0.073	-0.034
	Std Dev	0.009	0.027	0.026



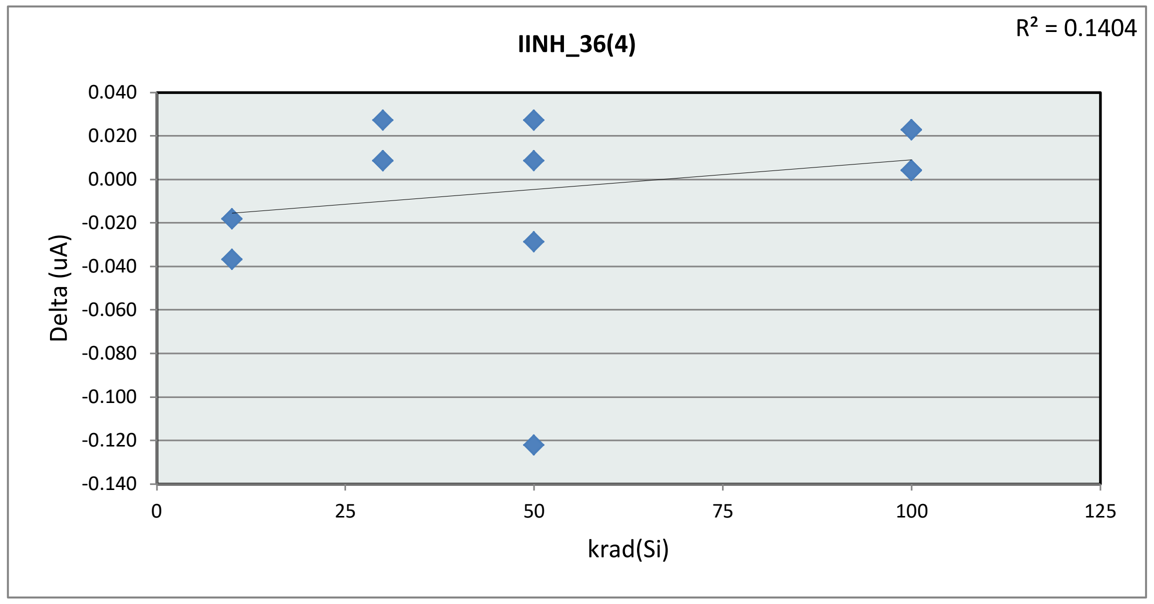
	IINH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.098	0.115	0.115	0.073
Average	0.124	0.126	0.133	0.120
Max	0.172	0.133	0.152	0.166
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
SN55LVCP22A-SP

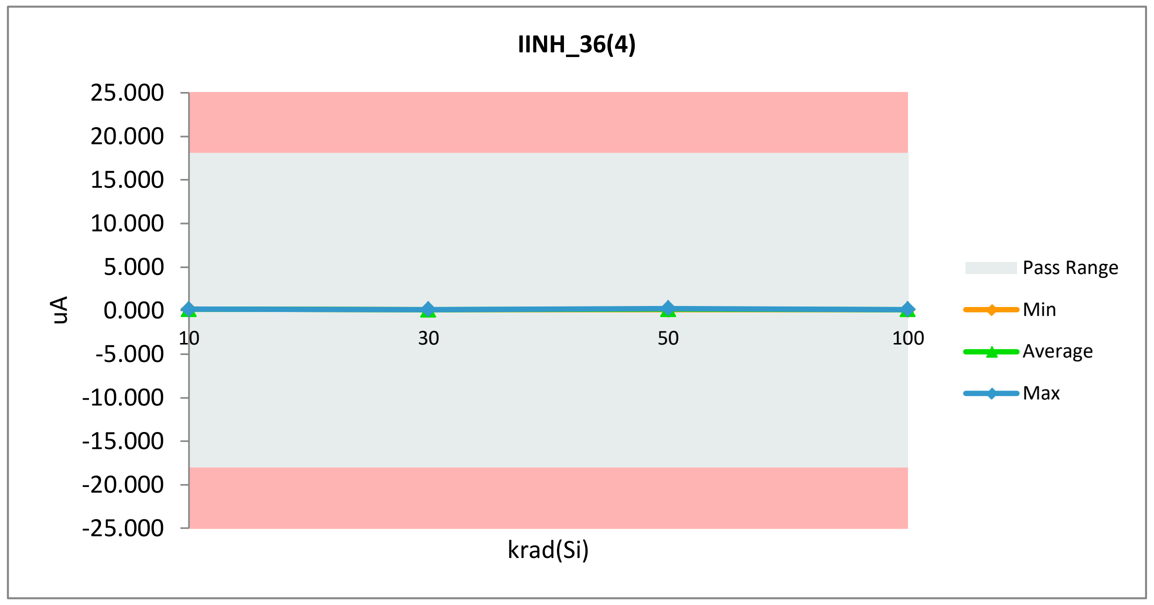
	IINH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.122	0.140	-0.018
10	2	0.141	0.159	-0.018
10	3	0.122	0.159	-0.037
10	4	0.122	0.140	-0.018
10	5	0.104	0.140	-0.037
30	1	0.126	0.099	0.027
30	2	0.108	0.099	0.009
30	3	0.126	0.118	0.009
30	4	0.126	0.118	0.009
30	5	0.108	0.099	0.009
50	11	0.108	0.137	-0.029
50	12	0.126	0.118	0.009
50	13	0.145	0.118	0.027
50	14	0.126	0.248	-0.122
50	15	0.145	0.118	0.027
100	22	0.104	0.099	0.004
100	23	0.122	0.118	0.004
100	24	0.122	0.118	0.004
100	25	0.141	0.118	0.023
100	26	0.122	0.118	0.004
100	27	0.141	0.118	0.023
100	28	0.104	0.099	0.004
100	29	0.160	0.137	0.023
100	30	0.122	0.099	0.023
100	31	0.122	0.099	0.023
100	32	0.104	0.099	0.004
100	33	0.122	0.118	0.004
100	34	0.122	0.118	0.004
100	35	0.122	0.118	0.004
100	36	0.122	0.118	0.004
100	37	0.122	0.118	0.004
100	38	0.122	0.118	0.004
100	39	0.104	0.099	0.004
100	41	0.141	0.118	0.023
100	42	0.122	0.118	0.004
100	43	0.122	0.118	0.004
100	44	0.141	0.137	0.004
	Max	0.160	0.248	0.027
	Average	0.124	0.123	0.001
	Min	0.104	0.099	-0.122
	Std Dev	0.013	0.027	0.027



	IINH_36(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	18	uA
Min Limit	-18	uA

krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.140	0.099	0.118	0.099
Average	0.148	0.107	0.148	0.115
Max	0.159	0.118	0.248	0.137
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
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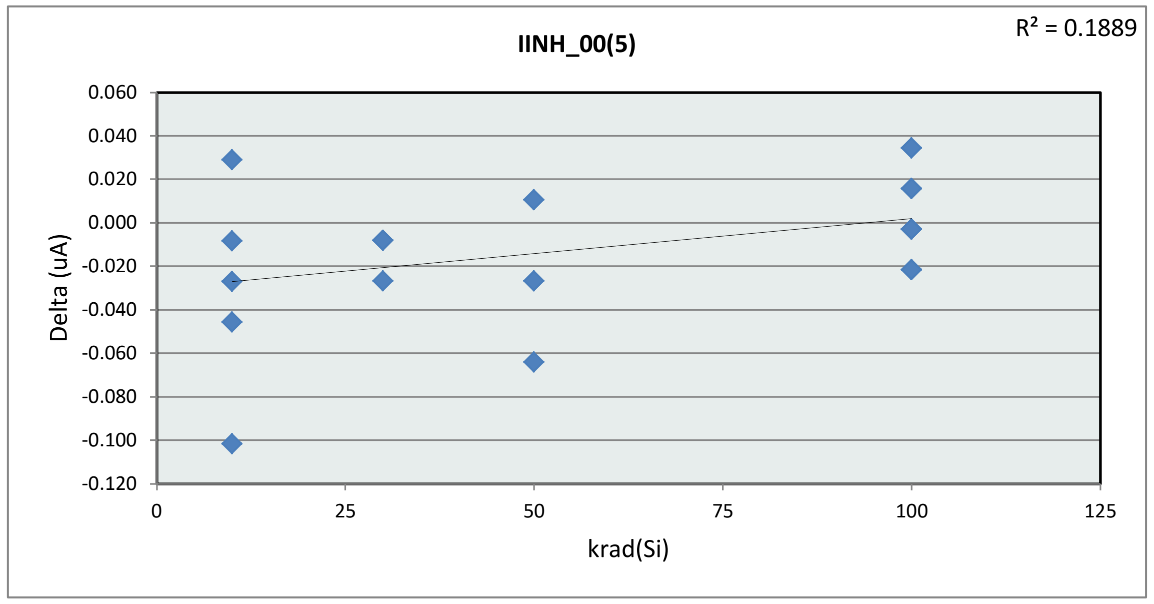
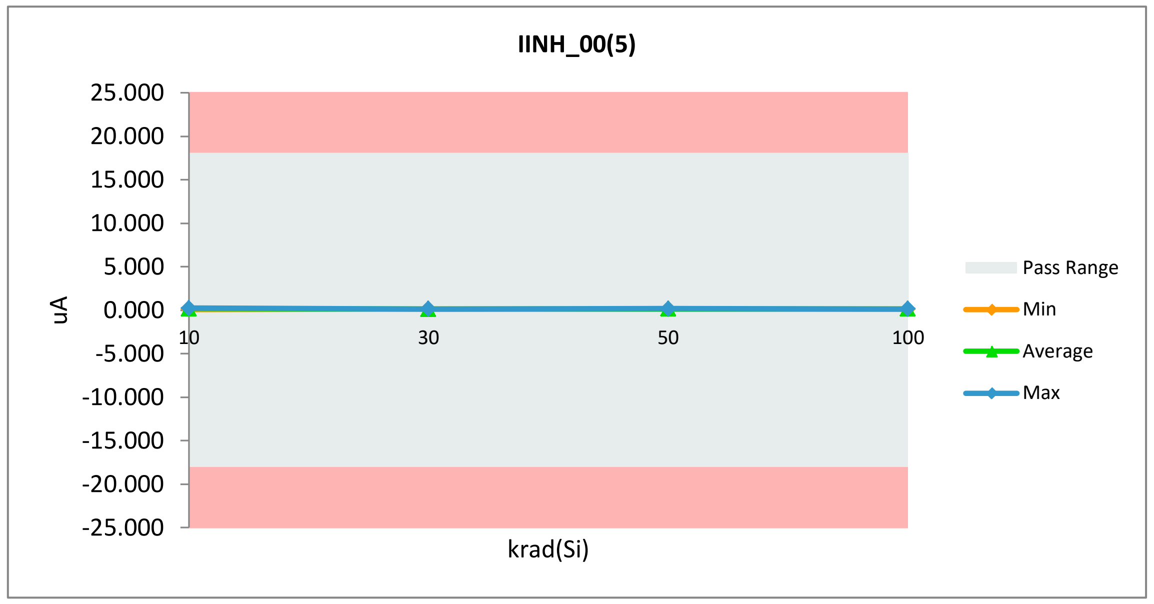
	IINH_00(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.148	0.175	-0.027
10	2	0.167	0.212	-0.046
10	3	0.148	0.250	-0.102
10	4	0.130	0.101	0.029
10	5	0.167	0.175	-0.008
30	1	0.125	0.133	-0.008
30	2	0.106	0.114	-0.008
30	3	0.143	0.151	-0.008
30	4	0.125	0.151	-0.027
30	5	0.106	0.114	-0.008
50	11	0.106	0.170	-0.064
50	12	0.143	0.133	0.010
50	13	0.143	0.133	0.010
50	14	0.125	0.151	-0.027
50	15	0.125	0.151	-0.027
100	22	0.130	0.133	-0.003
100	23	0.148	0.133	0.016
100	24	0.148	0.151	-0.003
100	25	0.167	0.151	0.016
100	26	0.148	0.151	-0.003
100	27	0.167	0.133	0.034
100	28	0.130	0.151	-0.022
100	29	0.167	0.133	0.034
100	30	0.148	0.151	-0.003
100	31	0.167	0.133	0.034
100	32	0.130	0.151	-0.022
100	33	0.148	0.151	-0.003
100	34	0.148	0.133	0.016
100	35	0.148	0.151	-0.003
100	36	0.148	0.151	-0.003
100	37	0.130	0.151	-0.022
100	38	0.130	0.151	-0.022
100	39	0.148	0.151	-0.003
100	41	0.130	0.151	-0.022
100	42	0.148	0.151	-0.003
100	43	0.148	0.133	0.016
100	44	0.167	0.151	0.016
	Max	0.167	0.250	0.034
	Average	0.142	0.149	-0.007
	Min	0.106	0.101	-0.102
	Std Dev	0.017	0.026	0.027

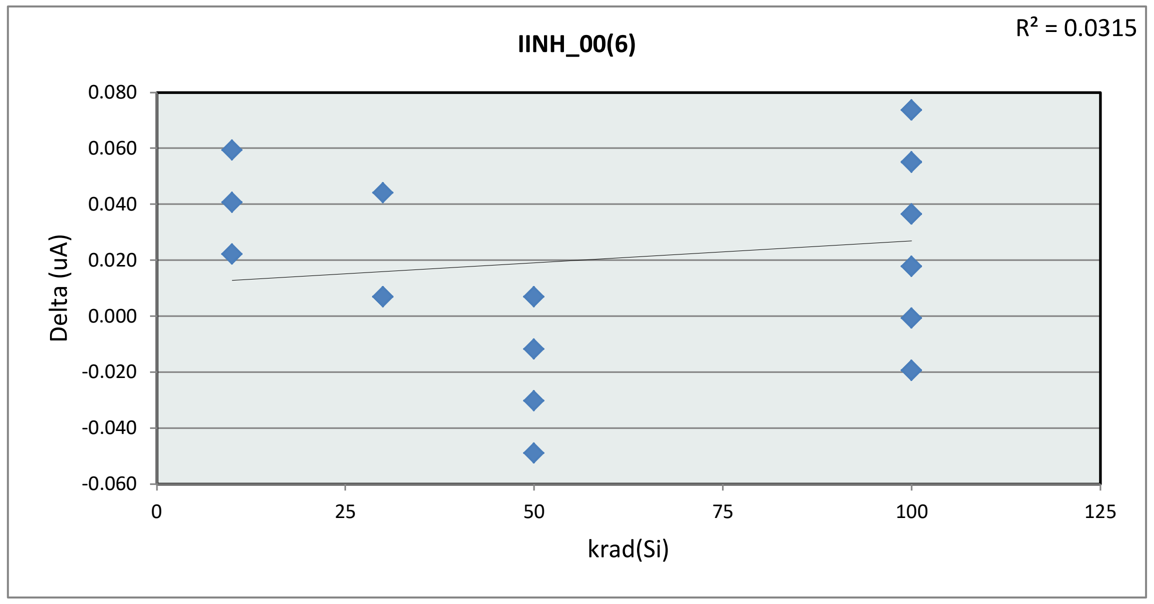


	IINH_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.101	0.114	0.133	0.133
Average	0.183	0.133	0.148	0.145
Max	0.250	0.151	0.170	0.151
UL	18.000	18.000	18.000	18.000

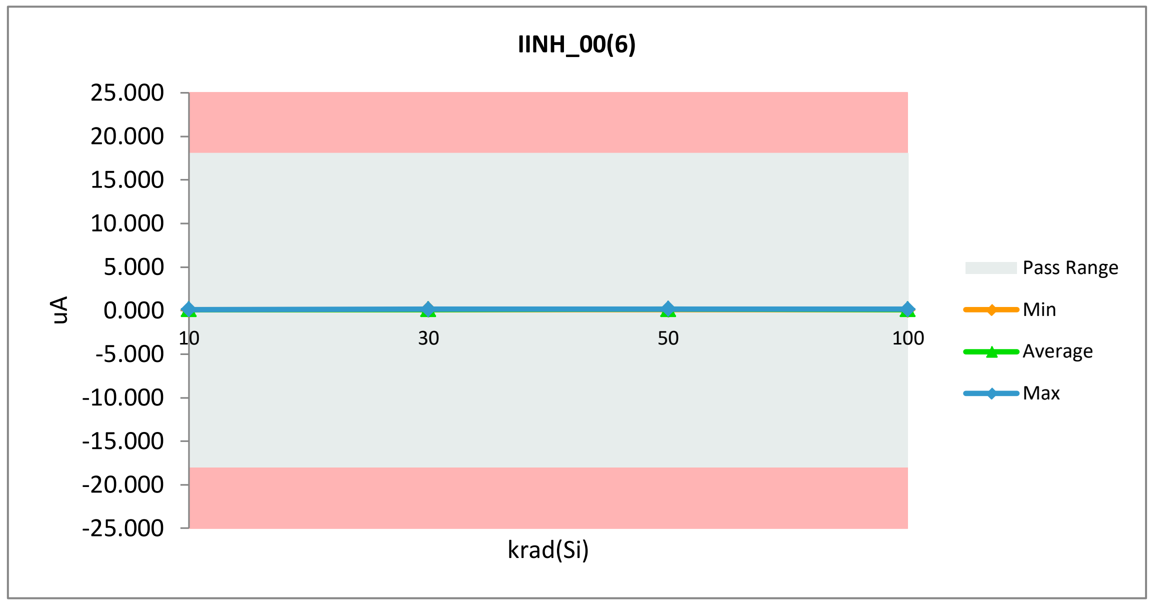


HDR Biased TID Report
SN55LVCP22A-SP

		IINH_00(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	0.138	0.116	0.022
10	2	0.175	0.134	0.041
10	3	0.138	0.116	0.022
10	4	0.175	0.116	0.059
10	5	0.119	0.097	0.022
30	1	0.145	0.138	0.007
30	2	0.126	0.119	0.007
30	3	0.145	0.138	0.007
30	4	0.182	0.138	0.044
30	5	0.163	0.157	0.007
50	11	0.126	0.119	0.007
50	12	0.182	0.175	0.007
50	13	0.163	0.194	-0.030
50	14	0.126	0.138	-0.012
50	15	0.145	0.194	-0.049
100	22	0.100	0.120	-0.019
100	23	0.138	0.120	0.018
100	24	0.193	0.120	0.074
100	25	0.156	0.120	0.036
100	26	0.193	0.120	0.074
100	27	0.193	0.120	0.074
100	28	0.119	0.101	0.018
100	29	0.193	0.138	0.055
100	30	0.156	0.120	0.036
100	31	0.138	0.101	0.036
100	32	0.156	0.120	0.036
100	33	0.175	0.101	0.074
100	34	0.175	0.138	0.036
100	35	0.175	0.120	0.055
100	36	0.119	0.120	-0.001
100	37	0.138	0.157	-0.019
100	38	0.119	0.120	-0.001
100	39	0.100	0.120	-0.019
100	41	0.138	0.120	0.018
100	42	0.100	0.120	-0.019
100	43	0.175	0.138	0.036
100	44	0.193	0.120	0.074
	Max	0.193	0.194	0.074
	Average	0.151	0.129	0.022
	Min	0.100	0.097	-0.049
	Std Dev	0.029	0.022	0.032



	IINH_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.097	0.119	0.119	0.101
Average	0.116	0.138	0.164	0.122
Max	0.134	0.157	0.194	0.157
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
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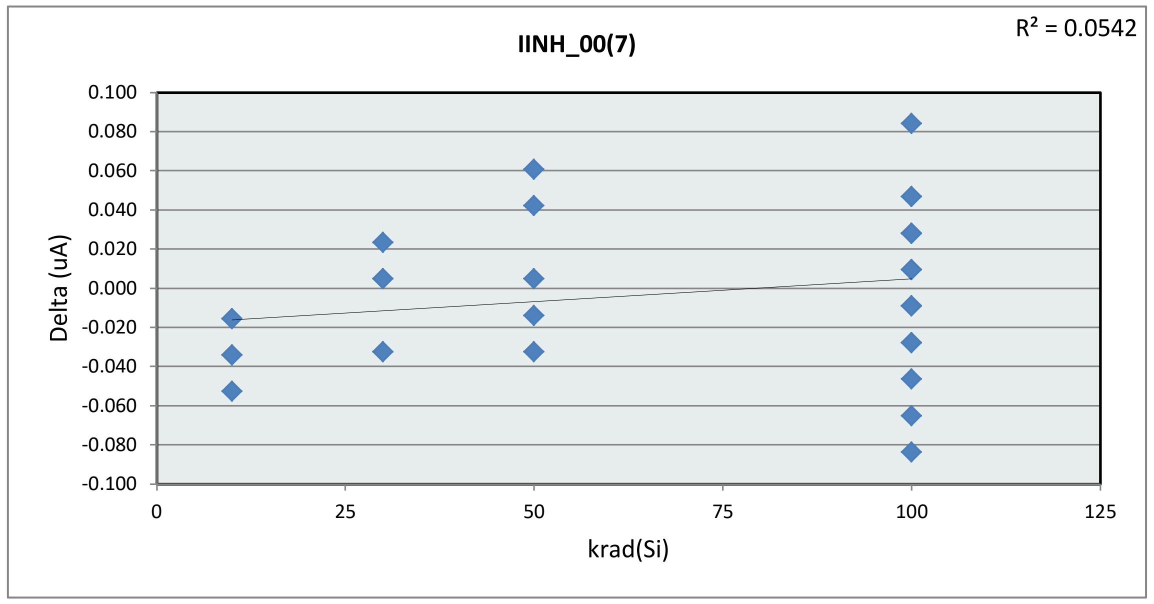
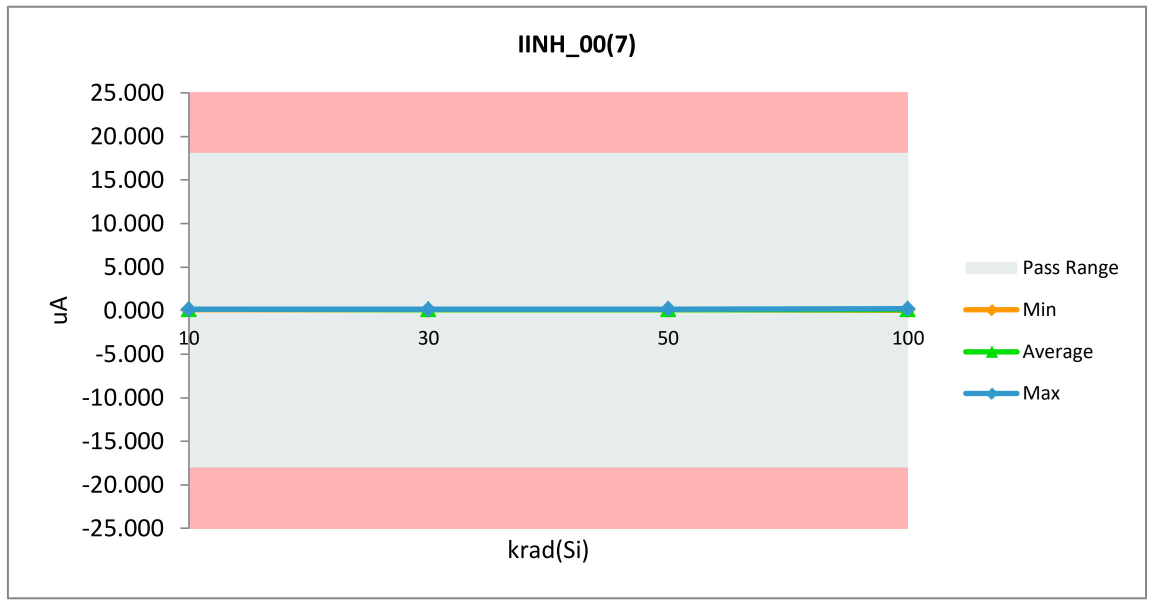
		IINH_00(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.101	0.153	-0.053
10	2	0.119	0.153	-0.034
10	3	0.119	0.153	-0.034
10	4	0.101	0.116	-0.016
10	5	0.101	0.116	-0.016
30	1	0.157	0.152	0.005
30	2	0.101	0.096	0.005
30	3	0.175	0.152	0.023
30	4	0.119	0.152	-0.033
30	5	0.082	0.115	-0.033
50	11	0.138	0.096	0.042
50	12	0.138	0.133	0.005
50	13	0.138	0.171	-0.033
50	14	0.138	0.152	-0.014
50	15	0.175	0.115	0.061
100	22	0.157	0.128	0.028
100	23	0.157	0.128	0.028
100	24	0.119	0.128	-0.009
100	25	0.157	0.128	0.028
100	26	0.157	0.147	0.009
100	27	0.119	0.091	0.028
100	28	0.157	0.110	0.047
100	29	0.157	0.184	-0.028
100	30	0.101	0.166	-0.065
100	31	0.119	0.203	-0.084
100	32	0.119	0.128	-0.009
100	33	0.119	0.091	0.028
100	34	0.119	0.091	0.028
100	35	0.119	0.147	-0.028
100	36	0.175	0.166	0.009
100	37	0.119	0.147	-0.028
100	38	0.157	0.073	0.084
100	39	0.157	0.110	0.047
100	41	0.101	0.110	-0.009
100	42	0.101	0.110	-0.009
100	43	0.119	0.110	0.009
100	44	0.119	0.166	-0.046
	Max	0.175	0.203	0.084
	Average	0.130	0.132	-0.002
	Min	0.082	0.073	-0.084
	Std Dev	0.025	0.029	0.036

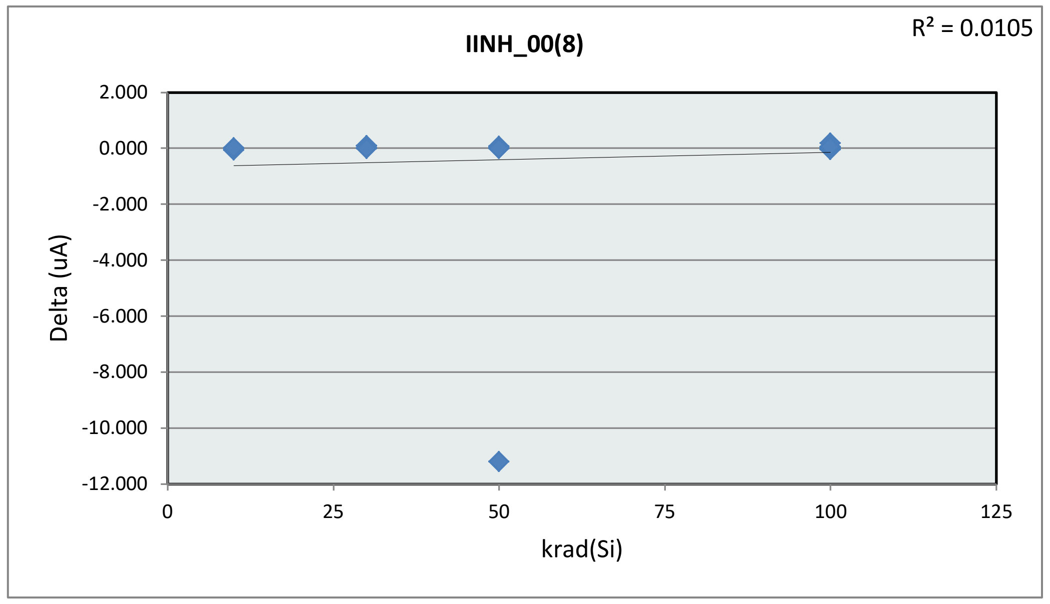


	IINH_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.116	0.096	0.096	0.073
Average	0.139	0.133	0.133	0.130
Max	0.153	0.152	0.171	0.203
UL	18.000	18.000	18.000	18.000

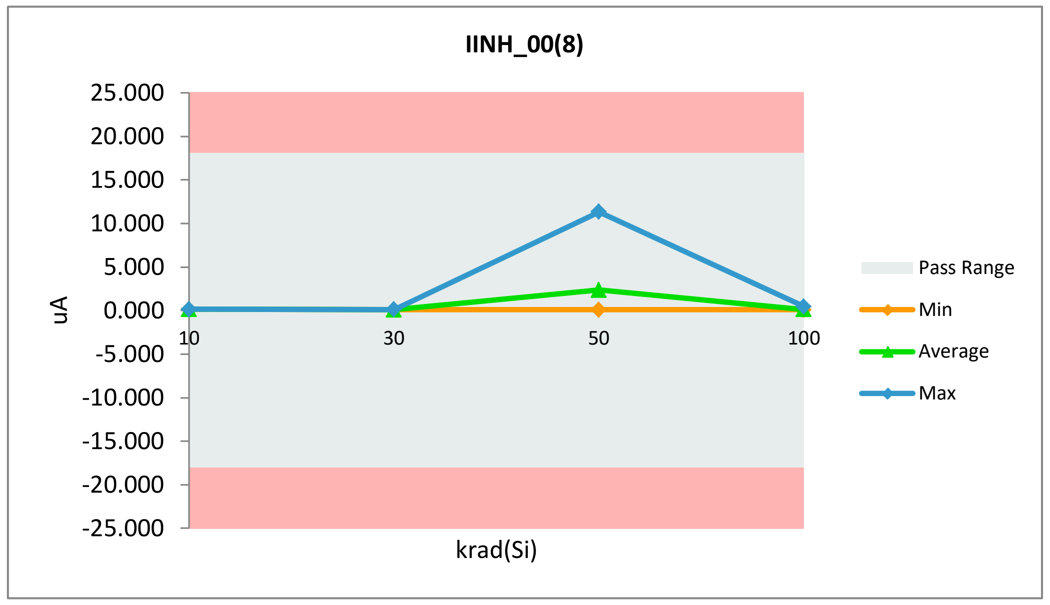


HDR Biased TID Report
SN55LVCP22A-SP

		IINH_00(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.066	0.140	-0.074
10	2	0.160	0.159	0.000
10	3	0.085	0.140	-0.056
10	4	0.122	0.140	-0.018
10	5	0.141	0.140	0.000
30	1	0.089	0.081	0.009
30	2	0.126	0.118	0.009
30	3	0.164	0.081	0.083
30	4	0.164	0.081	0.083
30	5	0.108	0.118	-0.010
50	11	0.145	0.081	0.064
50	12	0.145	0.155	-0.010
50	13	0.126	0.081	0.046
50	14	0.126	11.328	-11.202
50	15	0.108	0.118	-0.010
100	22	0.085	0.099	-0.014
100	23	0.085	0.118	-0.033
100	24	0.160	0.118	0.041
100	25	0.160	0.118	0.041
100	26	0.085	0.118	-0.033
100	27	0.085	0.118	-0.033
100	28	0.141	0.099	0.041
100	29	0.626	0.454	0.172
100	30	0.122	0.099	0.023
100	31	0.066	0.099	-0.033
100	32	0.141	0.099	0.041
100	33	0.066	0.099	-0.033
100	34	0.141	0.099	0.041
100	35	0.122	0.118	0.004
100	36	0.141	0.118	0.023
100	37	0.085	0.137	-0.052
100	38	0.085	0.099	-0.014
100	39	0.066	0.099	-0.033
100	41	0.327	0.305	0.023
100	42	0.141	0.118	0.023
100	43	0.085	0.118	-0.033
100	44	0.160	0.118	0.041
	Max	0.626	11.328	0.172
	Average	0.136	0.431	-0.294
	Min	0.066	0.081	-11.202
	Std Dev	0.095	1.842	1.844



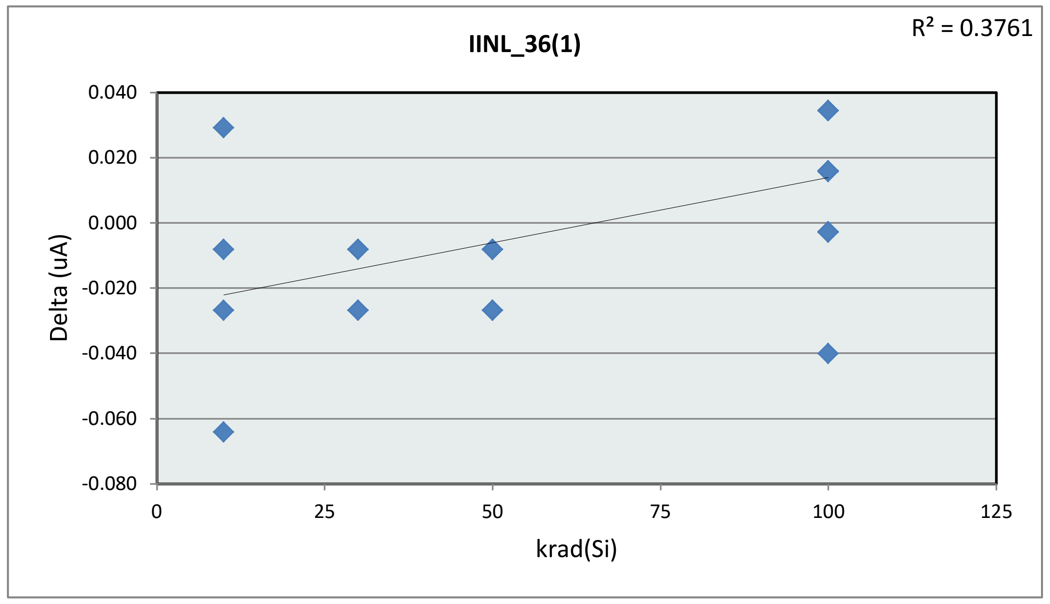
	IINH_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.140	0.081	0.081	0.099
Average	0.144	0.096	2.352	0.135
Max	0.159	0.118	11.328	0.454
UL	18.000	18.000	18.000	18.000



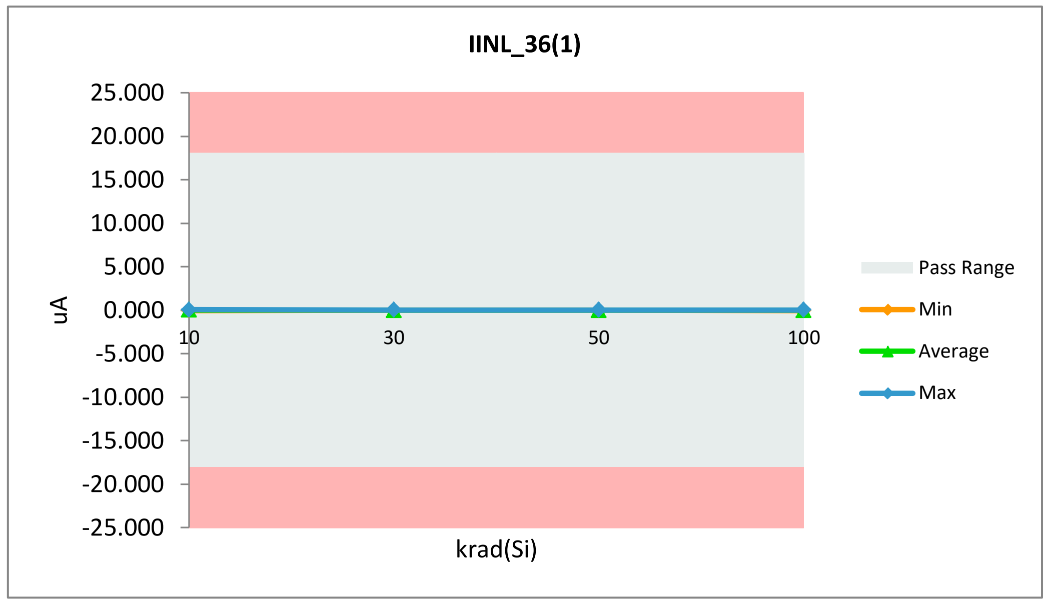
HDR Biased TID Report
SN55LVCP22A-SP

	IINL_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	0.018	0.026	-0.008
10	2	-0.001	0.026	-0.027
10	3	-0.001	-0.030	0.029
10	4	0.018	0.026	-0.008
10	5	-0.001	0.063	-0.064
30	1	-0.006	0.021	-0.027
30	2	-0.006	0.003	-0.008
30	3	-0.006	0.003	-0.008
30	4	-0.006	0.021	-0.027
30	5	0.013	0.021	-0.008
50	11	-0.006	0.003	-0.008
50	12	-0.006	0.003	-0.008
50	13	-0.006	0.021	-0.027
50	14	0.013	0.021	-0.008
50	15	-0.006	0.021	-0.027
100	22	-0.001	-0.017	0.016
100	23	-0.001	0.002	-0.003
100	24	-0.001	-0.017	0.016
100	25	0.018	-0.017	0.034
100	26	0.018	0.002	0.016
100	27	0.018	0.002	0.016
100	28	0.018	0.002	0.016
100	29	-0.001	-0.017	0.016
100	30	0.018	-0.017	0.034
100	31	0.018	0.002	0.016
100	32	0.018	-0.017	0.034
100	33	-0.001	-0.017	0.016
100	34	0.018	-0.017	0.034
100	35	-0.001	0.002	-0.003
100	36	0.018	-0.017	0.034
100	37	0.018	0.021	-0.003
100	38	-0.001	-0.017	0.016
100	39	-0.001	0.002	-0.003
100	41	0.018	-0.017	0.034
100	42	0.018	0.002	0.016
100	43	-0.001	-0.017	0.016
100	44	-0.001	0.039	-0.040
	Max	0.018	0.063	0.034
	Average	0.006	0.003	0.003
	Min	-0.006	-0.030	-0.064
	Std Dev	0.010	0.020	0.024



	IINL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.030	0.003	0.003	-0.017
Average	0.022	0.014	0.014	-0.006
Max	0.063	0.021	0.021	0.039
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
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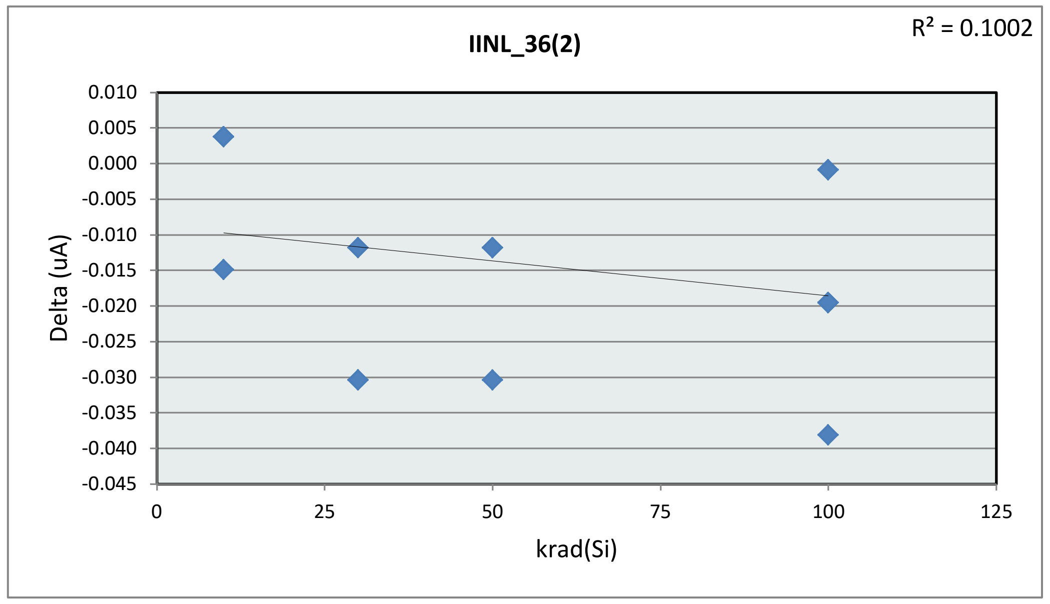
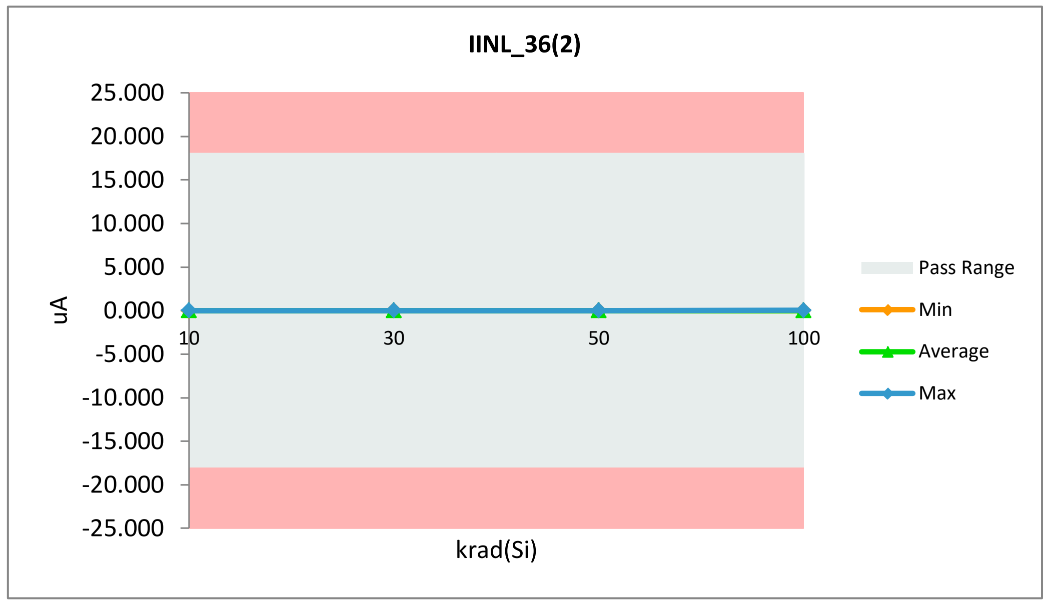
		IINL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.011	-0.015	0.004
10	2	-0.011	-0.015	0.004
10	3	-0.011	-0.015	0.004
10	4	-0.011	-0.015	0.004
10	5	-0.011	0.004	-0.015
30	1	-0.023	-0.011	-0.012
30	2	-0.023	0.008	-0.030
30	3	-0.023	-0.011	-0.012
30	4	-0.023	0.008	-0.030
30	5	-0.023	0.008	-0.030
50	11	-0.004	0.008	-0.012
50	12	-0.023	0.008	-0.030
50	13	-0.004	0.008	-0.012
50	14	-0.004	0.008	-0.012
50	15	-0.004	0.008	-0.012
100	22	-0.011	0.008	-0.020
100	23	-0.011	0.008	-0.020
100	24	-0.011	0.008	-0.020
100	25	-0.011	0.008	-0.020
100	26	-0.011	0.008	-0.020
100	27	-0.011	0.008	-0.020
100	28	-0.011	0.008	-0.020
100	29	-0.011	0.027	-0.038
100	30	-0.011	0.008	-0.020
100	31	0.007	0.045	-0.038
100	32	-0.011	0.008	-0.020
100	33	-0.011	0.008	-0.020
100	34	-0.011	0.008	-0.020
100	35	-0.011	0.008	-0.020
100	36	-0.011	0.008	-0.020
100	37	0.007	0.008	-0.001
100	38	0.007	0.008	-0.001
100	39	0.007	0.008	-0.001
100	41	-0.011	0.008	-0.020
100	42	-0.011	0.008	-0.020
100	43	0.007	0.008	-0.001
100	44	-0.011	0.008	-0.020
	Max	0.007	0.045	0.004
	Average	-0.010	0.006	-0.016
	Min	-0.023	-0.015	-0.038
	Std Dev	0.009	0.011	0.011

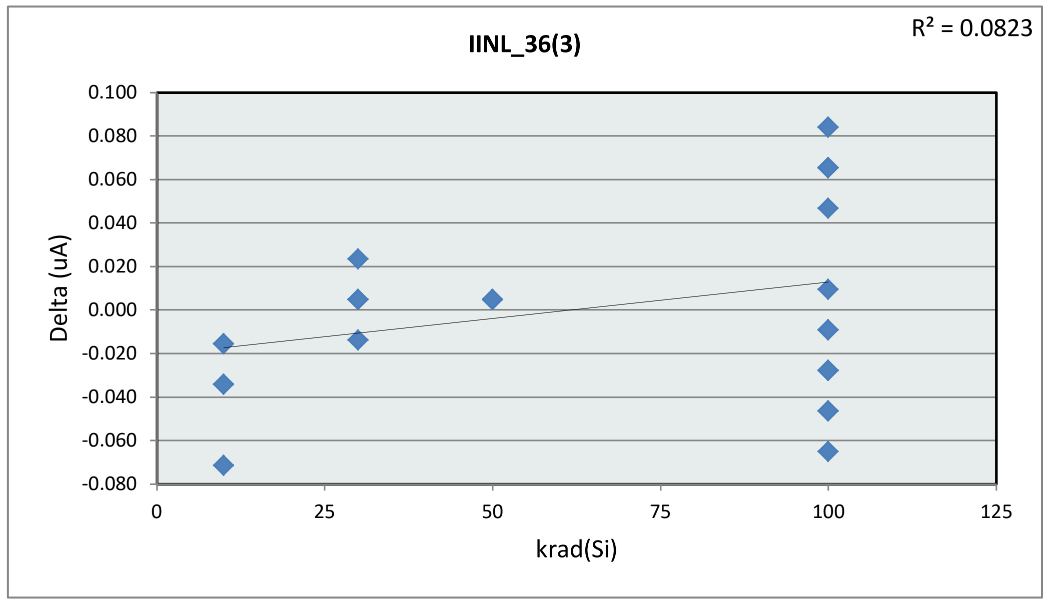


	IINL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.015	-0.011	0.008	0.008
Average	-0.011	0.000	0.008	0.011
Max	0.004	0.008	0.008	0.045
UL	18.000	18.000	18.000	18.000

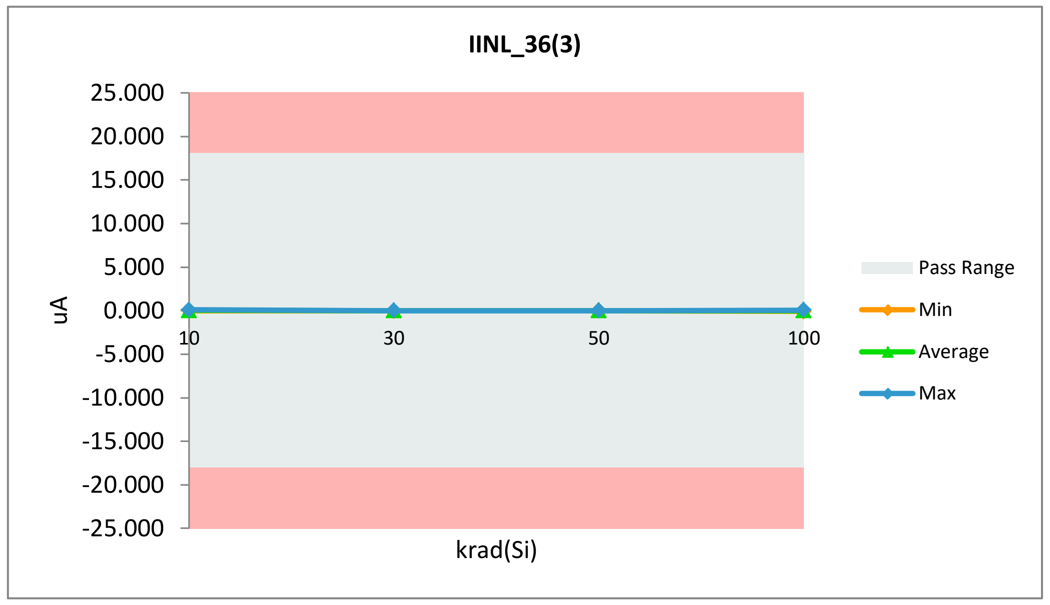


HDR Biased TID Report
SN55LVCP22A-SP

		IINL_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.007	0.042	-0.034
10	2	-0.011	0.004	-0.016
10	3	0.007	0.079	-0.072
10	4	-0.011	0.023	-0.034
10	5	-0.011	0.004	-0.016
30	1	0.008	0.003	0.005
30	2	0.008	0.003	0.005
30	3	0.008	0.003	0.005
30	4	-0.011	0.003	-0.014
30	5	0.008	-0.016	0.023
50	11	0.008	0.003	0.005
50	12	0.008	0.003	0.005
50	13	0.008	0.003	0.005
50	14	0.008	0.003	0.005
50	15	0.008	0.003	0.005
100	22	-0.011	-0.077	0.065
100	23	-0.011	0.035	-0.046
100	24	-0.011	-0.077	0.065
100	25	-0.011	0.017	-0.028
100	26	-0.011	0.017	-0.028
100	27	-0.011	-0.077	0.065
100	28	-0.011	-0.077	0.065
100	29	0.007	-0.002	0.009
100	30	0.007	-0.077	0.084
100	31	-0.011	0.017	-0.028
100	32	0.007	0.054	-0.046
100	33	0.007	0.035	-0.028
100	34	-0.011	0.017	-0.028
100	35	0.007	0.017	-0.009
100	36	-0.011	0.054	-0.065
100	37	-0.011	-0.077	0.065
100	38	0.007	-0.039	0.047
100	39	0.007	-0.077	0.084
100	41	-0.011	-0.002	-0.009
100	42	-0.011	-0.002	-0.009
100	43	0.007	0.054	-0.046
100	44	0.007	-0.058	0.065
	Max	0.008	0.079	0.084
	Average	-0.001	-0.004	0.003
	Min	-0.011	-0.077	-0.072
	Std Dev	0.009	0.043	0.043

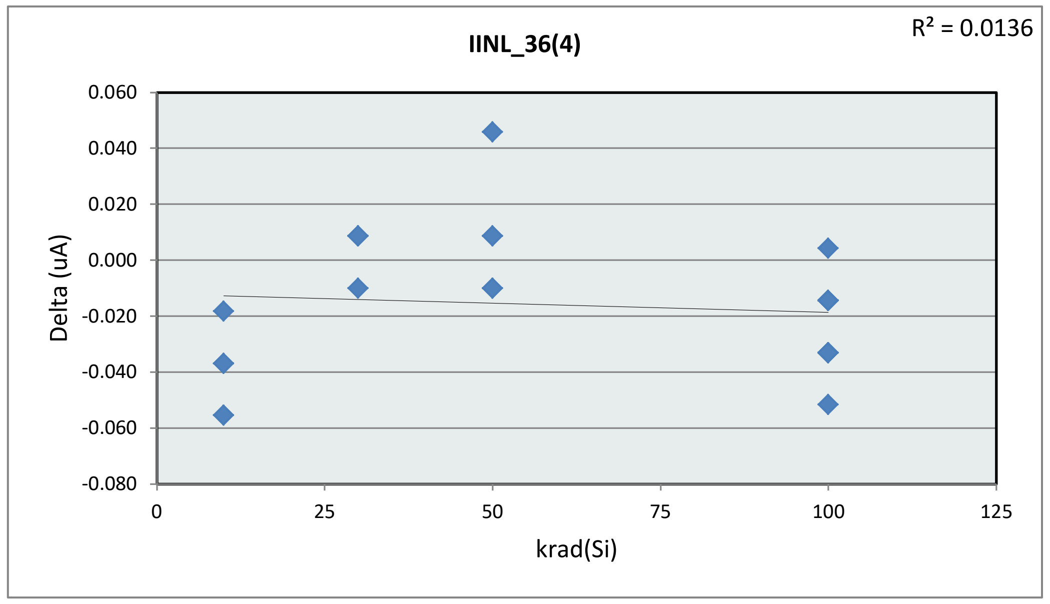


	IINL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.004	-0.016	0.003	-0.077
Average	0.031	-0.001	0.003	-0.015
Max	0.079	0.003	0.003	0.054
UL	18.000	18.000	18.000	18.000

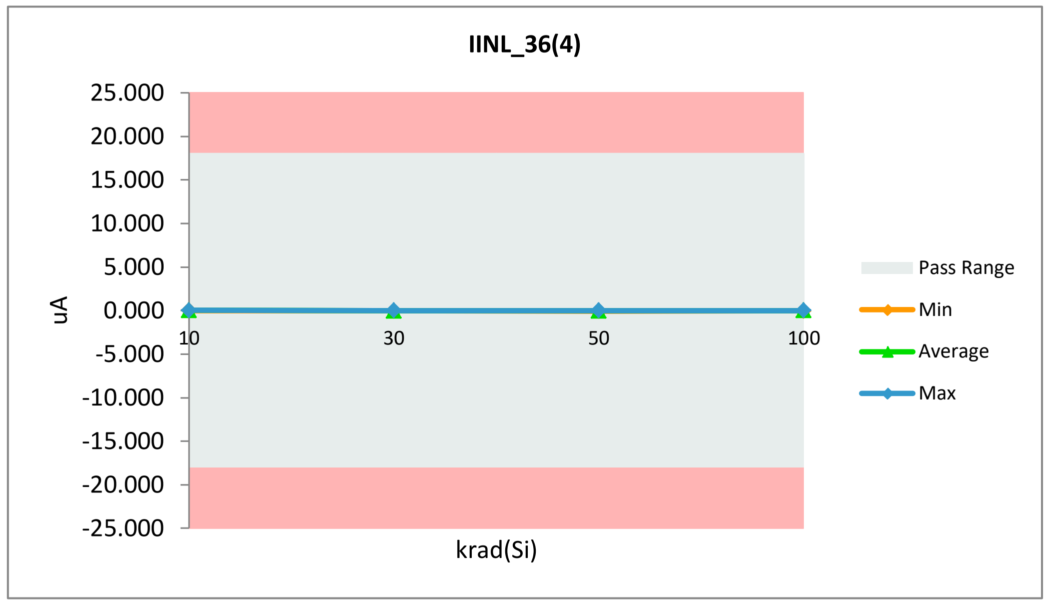


HDR Biased TID Report
SN55LVCP22A-SP

		IINL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.008	0.010	-0.018
10	2	-0.027	0.010	-0.037
10	3	-0.027	0.029	-0.056
10	4	-0.027	0.029	-0.056
10	5	-0.027	0.010	-0.037
30	1	-0.023	-0.031	0.009
30	2	-0.023	-0.031	0.009
30	3	-0.023	-0.031	0.009
30	4	-0.023	-0.031	0.009
30	5	-0.023	-0.013	-0.010
50	11	-0.023	-0.013	-0.010
50	12	-0.023	-0.013	-0.010
50	13	-0.023	-0.031	0.009
50	14	-0.023	-0.069	0.046
50	15	-0.023	-0.031	0.009
100	22	-0.027	0.006	-0.033
100	23	-0.027	0.006	-0.033
100	24	-0.027	-0.013	-0.014
100	25	-0.027	0.006	-0.033
100	26	-0.027	-0.013	-0.014
100	27	-0.027	-0.013	-0.014
100	28	-0.027	-0.013	-0.014
100	29	-0.083	-0.031	-0.052
100	30	-0.027	-0.013	-0.014
100	31	-0.027	0.006	-0.033
100	32	-0.027	-0.013	-0.014
100	33	-0.027	0.006	-0.033
100	34	-0.027	0.006	-0.033
100	35	-0.027	-0.013	-0.014
100	36	-0.027	0.006	-0.033
100	37	-0.027	-0.013	-0.014
100	38	-0.027	-0.013	-0.014
100	39	-0.027	-0.013	-0.014
100	41	-0.027	-0.031	0.004
100	42	-0.027	-0.013	-0.014
100	43	-0.027	0.006	-0.033
100	44	-0.027	-0.013	-0.014
	Max	-0.008	0.029	0.046
	Average	-0.027	-0.010	-0.017
	Min	-0.083	-0.069	-0.056
	Std Dev	0.010	0.019	0.021



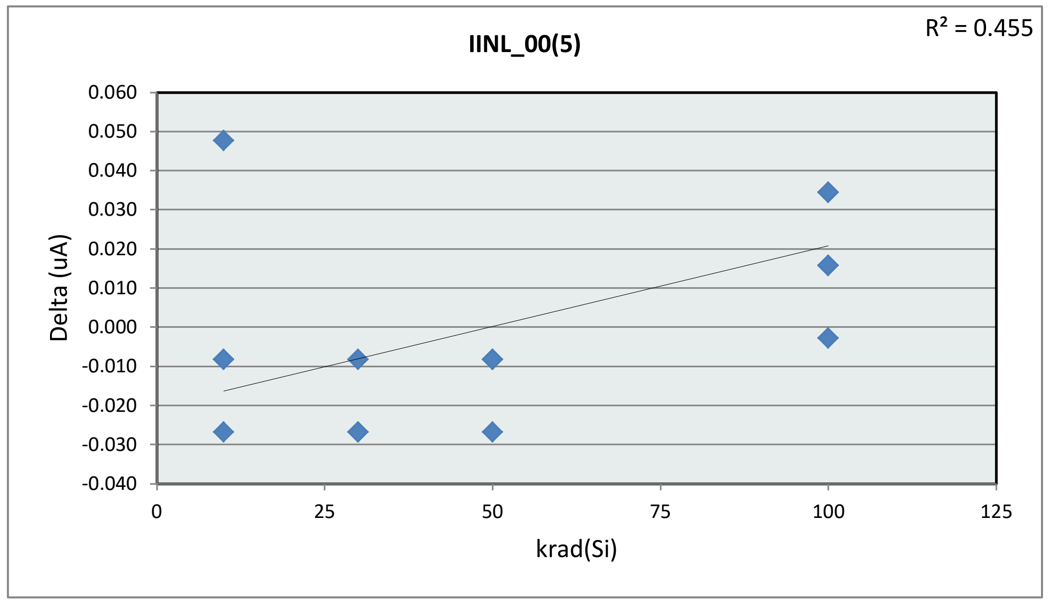
	IINL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.010	-0.031	-0.069	-0.031
Average	0.017	-0.028	-0.031	-0.007
Max	0.029	-0.013	-0.013	0.006
UL	18.000	18.000	18.000	18.000



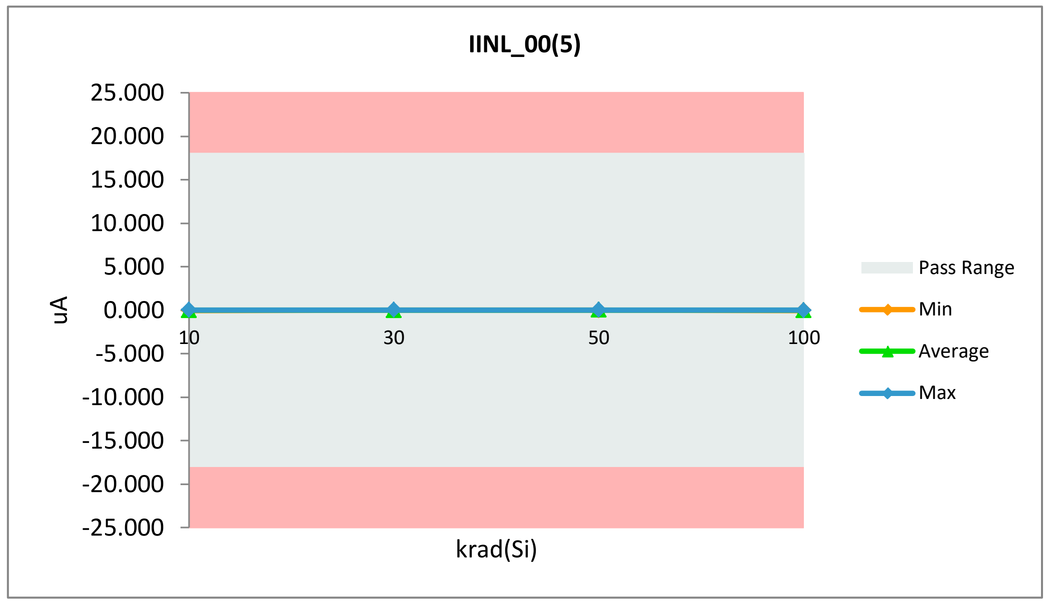
HDR Biased TID Report
SN55LVCP22A-SP

	IINL_00(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.001	0.007	-0.008
10	2	0.018	0.026	-0.008
10	3	0.018	0.026	-0.008
10	4	-0.001	0.026	-0.027
10	5	0.018	-0.030	0.048
30	1	-0.006	0.003	-0.008
30	2	-0.006	0.021	-0.027
30	3	-0.006	0.021	-0.027
30	4	-0.006	0.021	-0.027
30	5	-0.006	0.003	-0.008
50	11	-0.006	0.003	-0.008
50	12	0.013	0.021	-0.008
50	13	0.013	0.021	-0.008
50	14	-0.006	0.021	-0.027
50	15	0.013	0.021	-0.008
100	22	0.018	-0.017	0.034
100	23	0.018	-0.017	0.034
100	24	0.018	-0.017	0.034
100	25	0.018	0.002	0.016
100	26	-0.001	-0.017	0.016
100	27	-0.001	0.002	-0.003
100	28	0.018	-0.017	0.034
100	29	0.018	-0.017	0.034
100	30	-0.001	-0.017	0.016
100	31	0.018	-0.017	0.034
100	32	-0.001	-0.017	0.016
100	33	0.018	-0.017	0.034
100	34	-0.001	-0.017	0.016
100	35	0.018	-0.017	0.034
100	36	-0.001	-0.017	0.016
100	37	-0.001	-0.017	0.016
100	38	0.018	-0.017	0.034
100	39	0.018	0.002	0.016
100	41	-0.001	-0.017	0.016
100	42	-0.001	0.002	-0.003
100	43	0.018	0.002	0.016
100	44	0.018	-0.017	0.034
	Max	0.018	0.026	0.048
	Average	0.007	-0.002	0.009
	Min	-0.006	-0.030	-0.027
	Std Dev	0.010	0.017	0.022



	IINL_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.030	0.003	0.003	-0.017
Average	0.011	0.014	0.017	-0.012
Max	0.026	0.021	0.021	0.002
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
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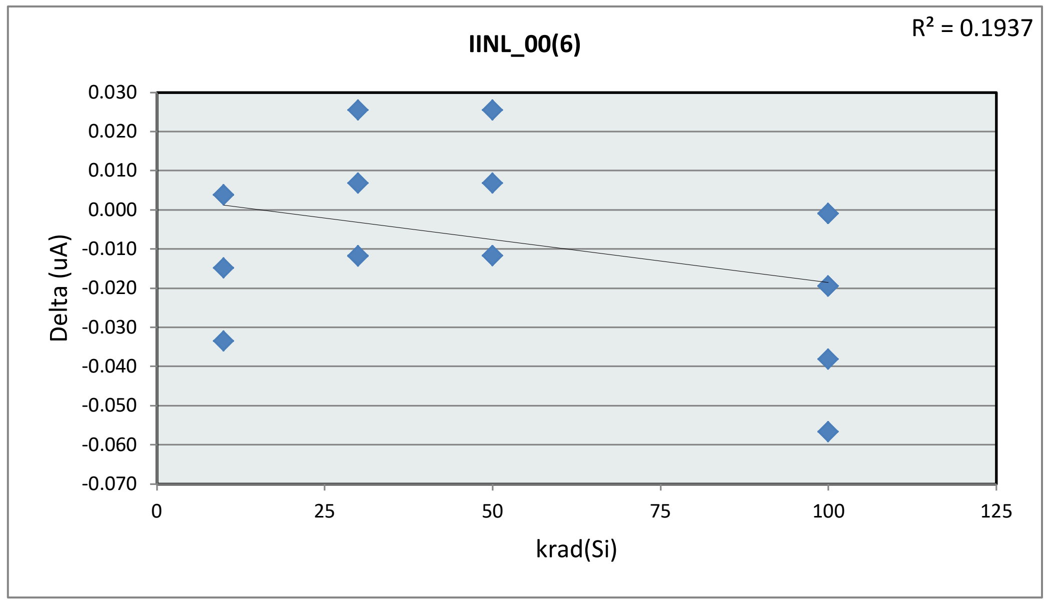
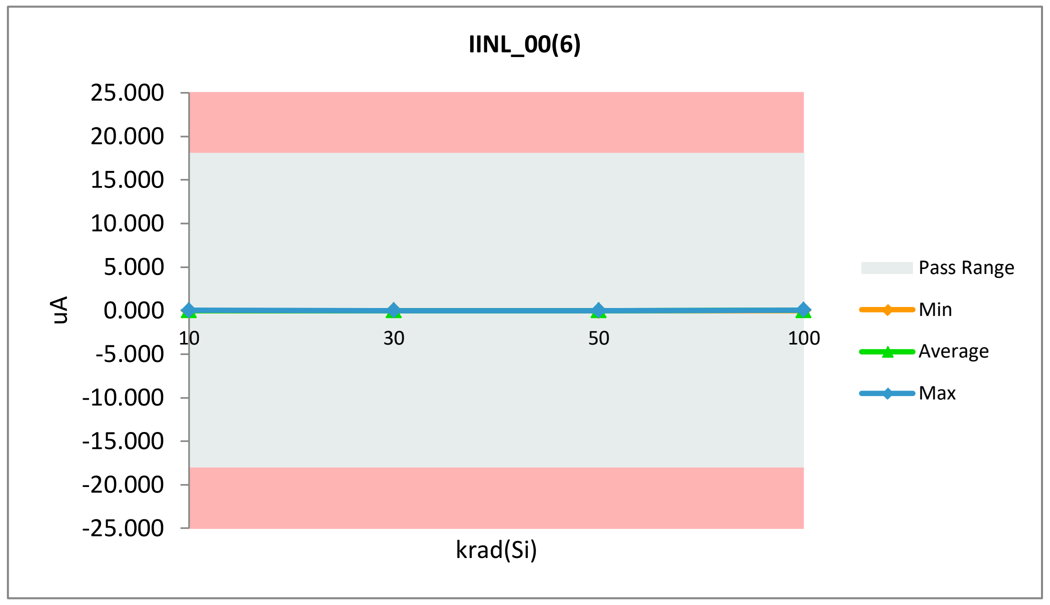
		IINL_00(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.011	-0.015	0.004
10	2	-0.011	-0.015	0.004
10	3	0.007	0.041	-0.034
10	4	-0.011	0.004	-0.015
10	5	-0.011	-0.015	0.004
30	1	-0.023	-0.011	-0.012
30	2	-0.004	-0.011	0.007
30	3	-0.004	-0.011	0.007
30	4	-0.004	0.008	-0.012
30	5	0.014	-0.011	0.025
50	11	-0.004	0.008	-0.012
50	12	-0.004	-0.011	0.007
50	13	-0.004	0.008	-0.012
50	14	-0.004	0.008	-0.012
50	15	-0.004	-0.030	0.025
100	22	0.007	0.008	-0.001
100	23	0.007	0.008	-0.001
100	24	0.007	0.008	-0.001
100	25	-0.030	0.027	-0.057
100	26	0.007	0.027	-0.020
100	27	-0.011	0.008	-0.020
100	28	0.007	0.008	-0.001
100	29	0.007	0.008	-0.001
100	30	-0.011	0.027	-0.038
100	31	-0.011	0.008	-0.020
100	32	-0.011	0.008	-0.020
100	33	-0.011	0.027	-0.038
100	34	-0.011	0.008	-0.020
100	35	-0.011	0.008	-0.020
100	36	0.007	0.008	-0.001
100	37	0.007	0.027	-0.020
100	38	0.007	0.064	-0.057
100	39	0.007	0.027	-0.020
100	41	-0.011	0.008	-0.020
100	42	-0.011	0.008	-0.020
100	43	-0.011	0.008	-0.020
100	44	-0.011	0.008	-0.020
	Max	0.014	0.064	0.025
	Average	-0.004	0.008	-0.012
	Min	-0.030	-0.030	-0.057
	Std Dev	0.010	0.018	0.018



	IINL_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.015	-0.011	-0.030	0.008
Average	0.000	-0.007	-0.003	0.016
Max	0.041	0.008	0.008	0.064
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
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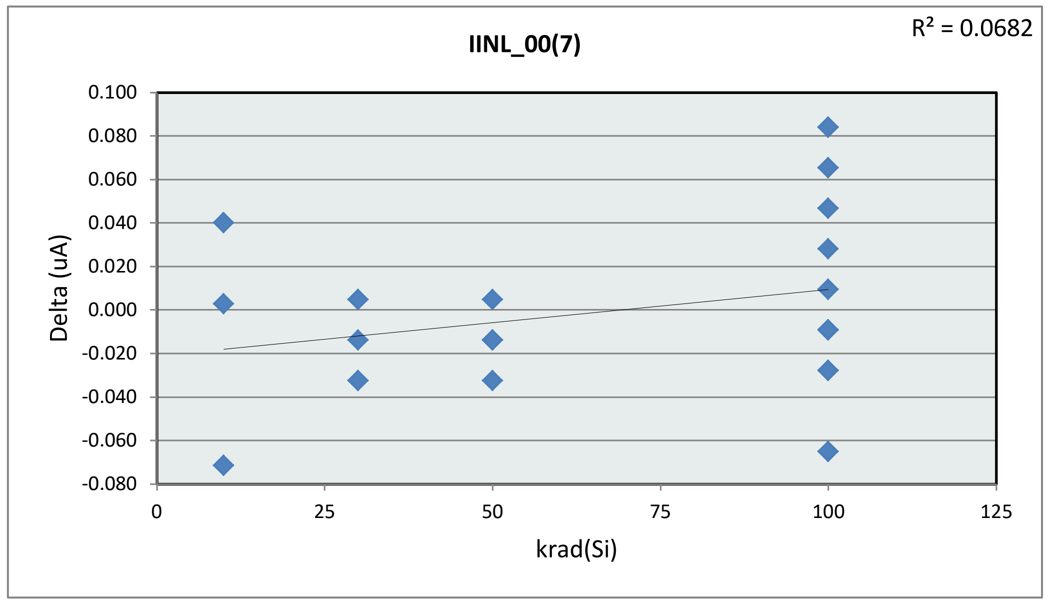
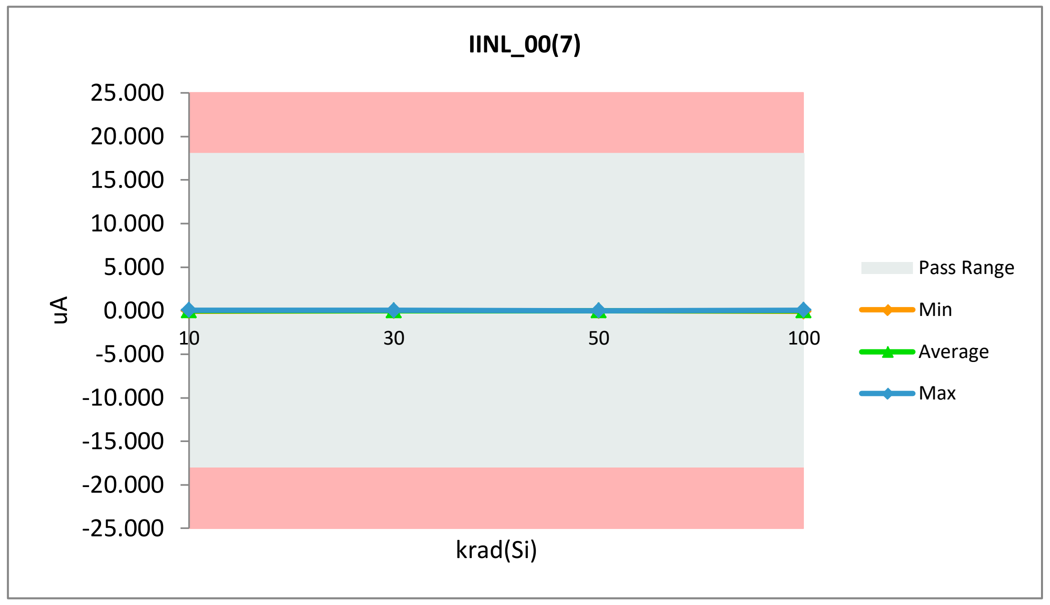
	IINL_00(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	0.026	-0.014	0.040
10	2	-0.011	-0.014	0.003
10	3	-0.030	0.042	-0.072
10	4	-0.011	-0.051	0.040
10	5	-0.011	0.060	-0.072
30	1	-0.011	0.021	-0.033
30	2	-0.011	0.021	-0.033
30	3	-0.011	-0.016	0.005
30	4	-0.011	0.003	-0.014
30	5	0.008	0.003	0.005
50	11	-0.011	0.003	-0.014
50	12	-0.011	0.003	-0.014
50	13	-0.030	0.003	-0.033
50	14	-0.011	0.003	-0.014
50	15	-0.011	-0.016	0.005
100	22	-0.011	-0.058	0.047
100	23	0.007	-0.077	0.084
100	24	0.007	0.035	-0.028
100	25	0.007	-0.002	0.009
100	26	-0.011	-0.077	0.065
100	27	-0.011	-0.002	-0.009
100	28	0.007	0.017	-0.009
100	29	0.007	-0.021	0.028
100	30	0.007	-0.077	0.084
100	31	0.007	-0.002	0.009
100	32	0.007	0.017	-0.009
100	33	-0.011	0.017	-0.028
100	34	0.007	0.017	-0.009
100	35	-0.030	-0.002	-0.028
100	36	0.007	-0.077	0.084
100	37	-0.011	-0.002	-0.009
100	38	0.007	0.017	-0.009
100	39	-0.011	0.054	-0.065
100	41	-0.011	0.017	-0.028
100	42	-0.011	0.054	-0.065
100	43	0.007	-0.039	0.047
100	44	-0.011	-0.077	0.065
	Max	0.026	0.060	0.084
	Average	-0.005	-0.006	0.001
	Min	-0.030	-0.077	-0.072
	Std Dev	0.012	0.038	0.042

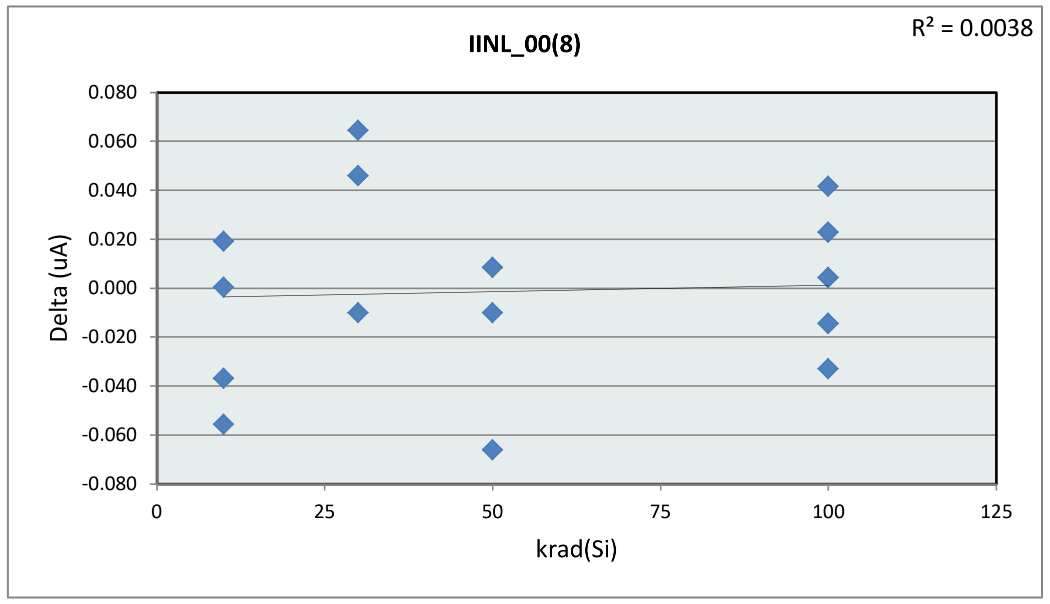


	IINL_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.051	-0.016	-0.016	-0.077
Average	0.004	0.006	-0.001	-0.012
Max	0.060	0.021	0.003	0.054
UL	18.000	18.000	18.000	18.000

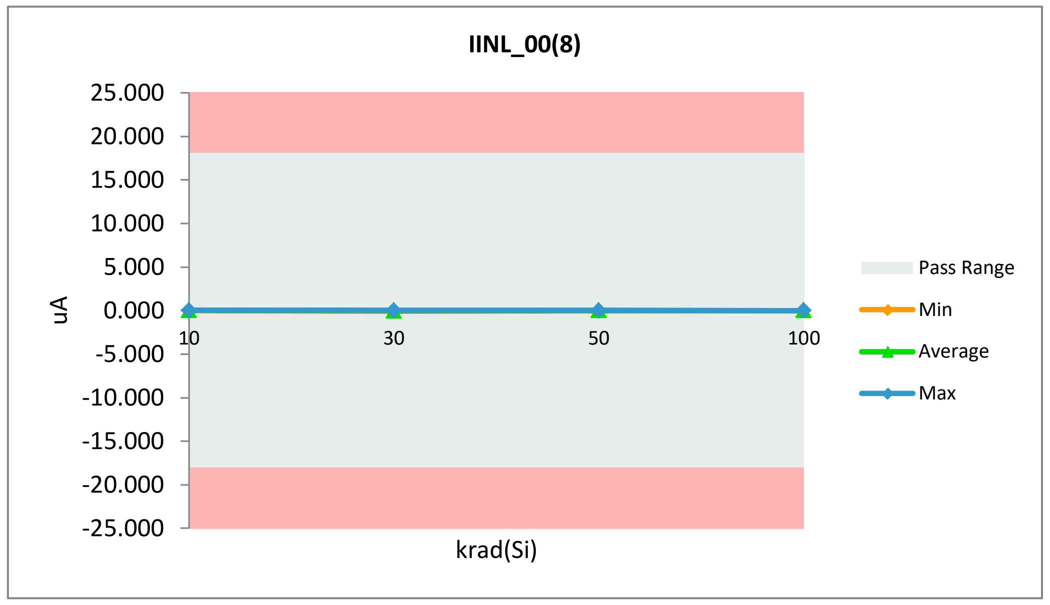


HDR Biased TID Report
SN55LVCP22A-SP

		IINL_00(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.029	0.010	0.019
10	2	-0.008	0.029	-0.037
10	3	-0.046	0.010	-0.056
10	4	-0.008	0.029	-0.037
10	5	0.010	0.010	0.000
30	1	0.014	0.025	-0.010
30	2	0.014	-0.031	0.046
30	3	0.014	-0.050	0.064
30	4	0.014	-0.031	0.046
30	5	0.014	-0.031	0.046
50	11	-0.041	0.025	-0.066
50	12	-0.041	0.025	-0.066
50	13	0.014	0.006	0.009
50	14	-0.004	-0.013	0.009
50	15	-0.041	-0.031	-0.010
100	22	-0.027	-0.013	-0.014
100	23	-0.027	-0.013	-0.014
100	24	-0.027	-0.013	-0.014
100	25	0.029	0.006	0.023
100	26	-0.027	-0.013	-0.014
100	27	0.010	0.006	0.004
100	28	-0.008	0.006	-0.014
100	29	-0.008	0.006	-0.014
100	30	0.029	0.006	0.023
100	31	-0.027	0.006	-0.033
100	32	0.010	-0.013	0.023
100	33	0.029	0.006	0.023
100	34	0.029	0.006	0.023
100	35	0.029	-0.013	0.042
100	36	-0.008	-0.013	0.004
100	37	-0.027	-0.013	-0.014
100	38	-0.008	-0.013	0.004
100	39	-0.046	-0.013	-0.033
100	41	0.029	-0.013	0.042
100	42	-0.008	-0.013	0.004
100	43	-0.008	-0.013	0.004
100	44	-0.027	-0.013	-0.014
	Max	0.029	0.029	0.064
	Average	-0.004	-0.004	0.000
	Min	-0.046	-0.050	-0.066
	Std Dev	0.025	0.018	0.031



	IINL_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.010	-0.050	-0.031	-0.013
Average	0.017	-0.024	0.002	-0.006
Max	0.029	0.025	0.025	0.006
UL	18.000	18.000	18.000	18.000



HDR Biased TID Report
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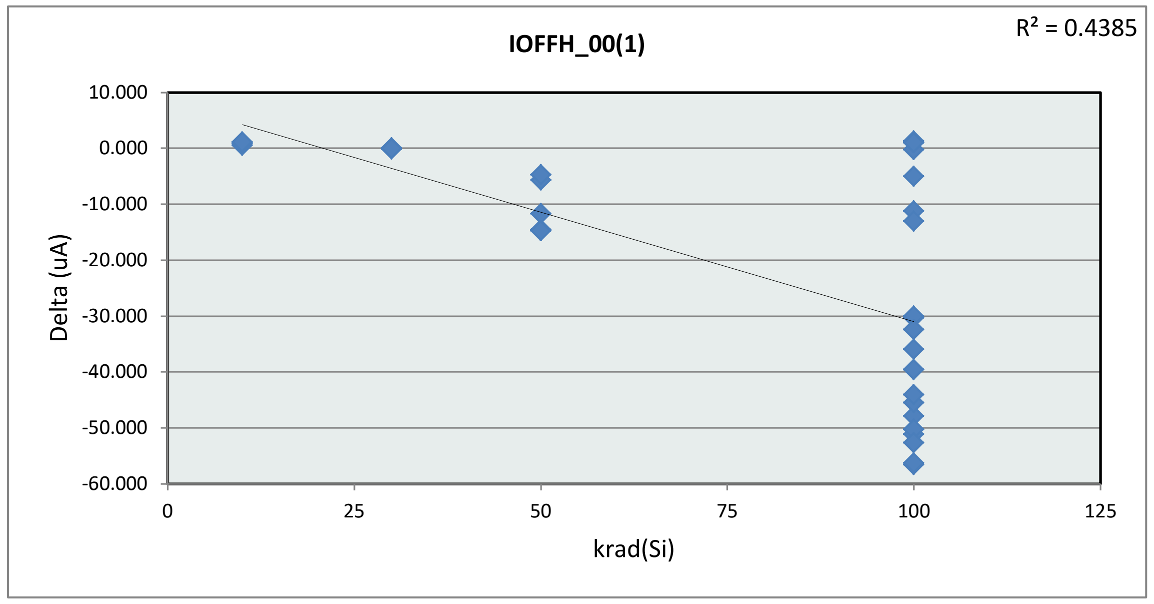
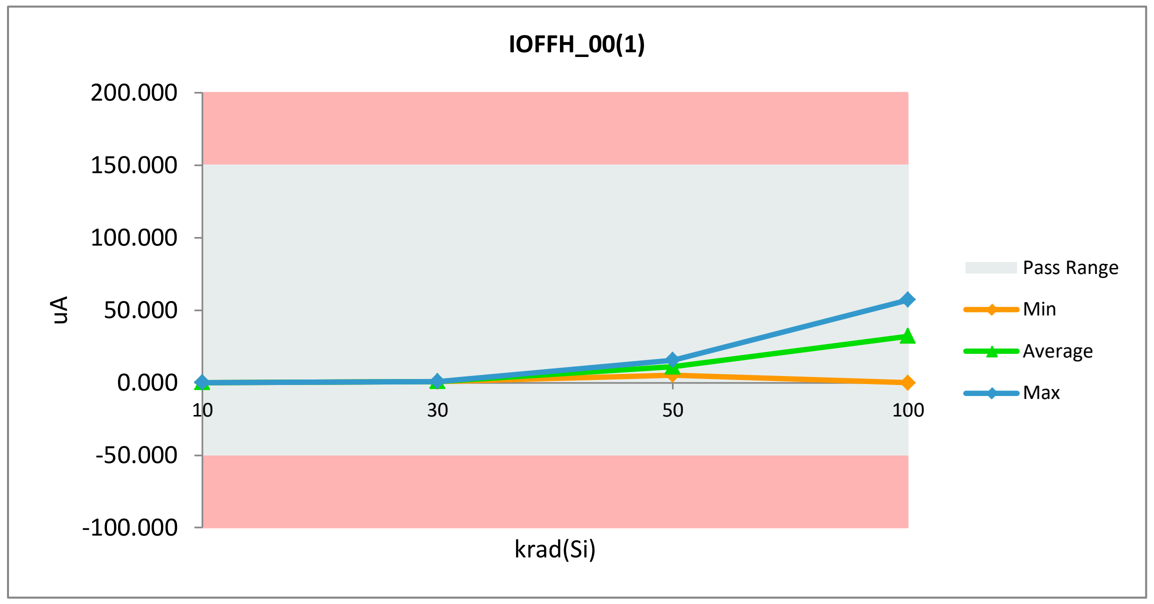
		IOFFH_00(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.545	0.071	0.474
10	2	1.146	0.071	1.075
10	3	0.845	0.071	0.775
10	4	1.146	0.071	1.075
10	5	1.146	0.071	1.075
30	1	0.747	0.756	-0.008
30	2	0.766	0.718	0.048
30	3	0.692	0.849	-0.157
30	4	0.785	0.830	-0.045
30	5	0.766	0.830	-0.064
50	11	0.692	15.236	-14.544
50	12	0.803	12.531	-11.728
50	13	0.803	6.522	-5.719
50	14	0.617	5.320	-4.703
50	15	0.747	15.536	-14.789
100	22	0.845	48.754	-47.909
100	23	0.845	51.137	-50.292
100	24	0.545	30.875	-30.330
100	25	0.545	11.805	-11.260
100	26	0.845	5.845	-5.000
100	27	0.845	1.078	-0.233
100	28	0.845	-0.114	0.959
100	29	1.146	-0.114	1.260
100	30	0.845	46.370	-45.525
100	31	0.845	36.835	-35.990
100	32	1.146	52.329	-51.183
100	33	0.845	40.410	-39.565
100	34	0.845	30.875	-30.030
100	35	0.845	33.259	-32.414
100	36	0.545	57.097	-56.552
100	37	1.146	14.189	-13.043
100	38	0.845	-0.114	0.959
100	39	0.845	51.137	-50.292
100	41	0.845	57.097	-56.252
100	42	0.845	53.521	-52.676
100	43	1.146	45.178	-44.032
100	44	0.845	40.410	-39.565
	Max	1.146	57.097	1.260
	Average	0.842	20.739	-19.897
	Min	0.545	-0.114	-56.552
	Std Dev	0.177	21.553	21.554

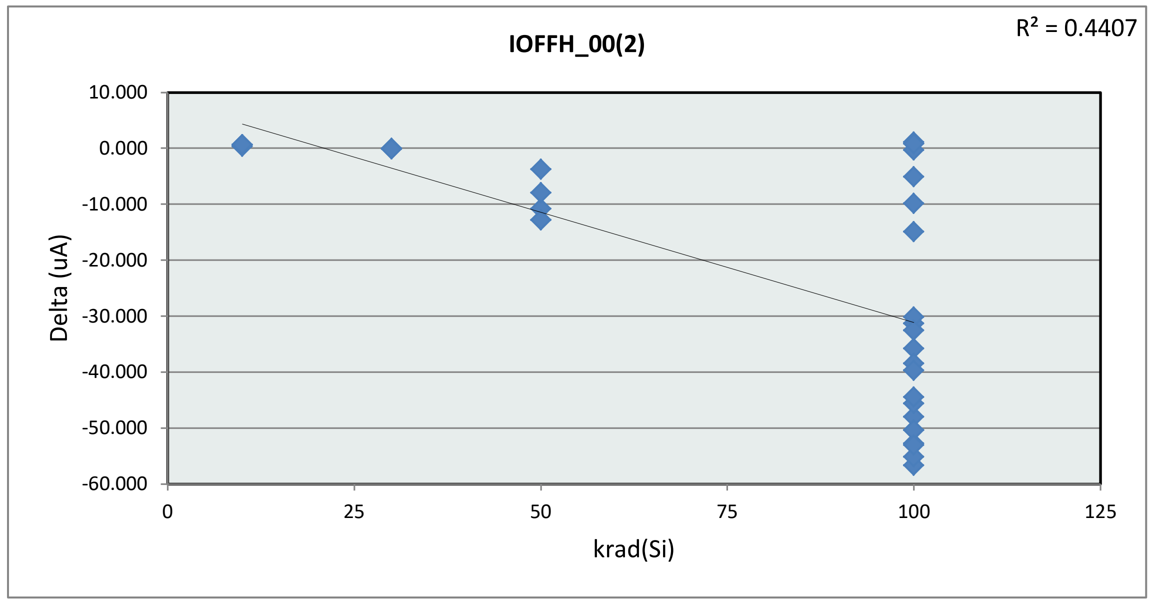


	IOFFH_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.071	0.718	5.320	-0.114
Average	0.071	0.796	11.029	32.175
Max	0.071	0.849	15.536	57.097
UL	150.000	150.000	150.000	150.000

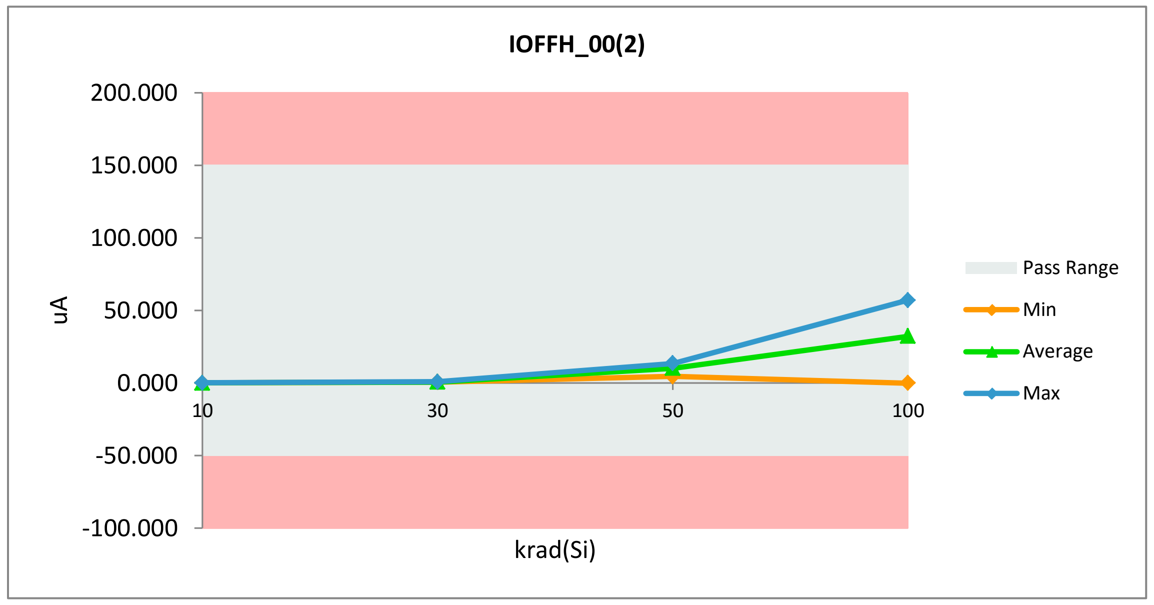


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.835	0.182	0.652
10	2	0.835	0.182	0.652
10	3	0.534	0.182	0.352
10	4	0.835	0.182	0.652
10	5	0.835	0.182	0.652
30	1	0.814	0.840	-0.027
30	2	0.702	0.766	-0.064
30	3	0.776	0.933	-0.157
30	4	0.795	0.803	-0.008
30	5	0.720	0.896	-0.175
50	11	0.720	13.560	-12.840
50	12	0.665	11.456	-10.791
50	13	0.739	8.750	-8.011
50	14	0.739	4.541	-3.802
50	15	0.683	13.560	-12.877
100	22	0.835	48.850	-48.015
100	23	0.835	51.233	-50.398
100	24	0.835	32.175	-31.340
100	25	0.835	10.736	-9.901
100	26	0.835	5.972	-5.137
100	27	0.835	1.207	-0.372
100	28	0.835	0.016	0.818
100	29	1.135	0.016	1.119
100	30	0.835	46.468	-45.633
100	31	1.135	36.940	-35.805
100	32	0.835	53.615	-52.780
100	33	0.835	39.322	-38.487
100	34	0.835	30.984	-30.149
100	35	0.835	33.366	-32.531
100	36	0.534	57.188	-56.654
100	37	0.534	15.500	-14.966
100	38	0.835	0.016	0.818
100	39	0.835	51.233	-50.398
100	41	0.835	55.997	-55.162
100	42	0.534	53.615	-53.081
100	43	0.835	45.277	-44.442
100	44	0.835	40.513	-39.678
	Max	1.135	57.188	1.119
	Average	0.792	20.737	-19.945
	Min	0.534	0.016	-56.654
	Std Dev	0.128	21.566	21.568

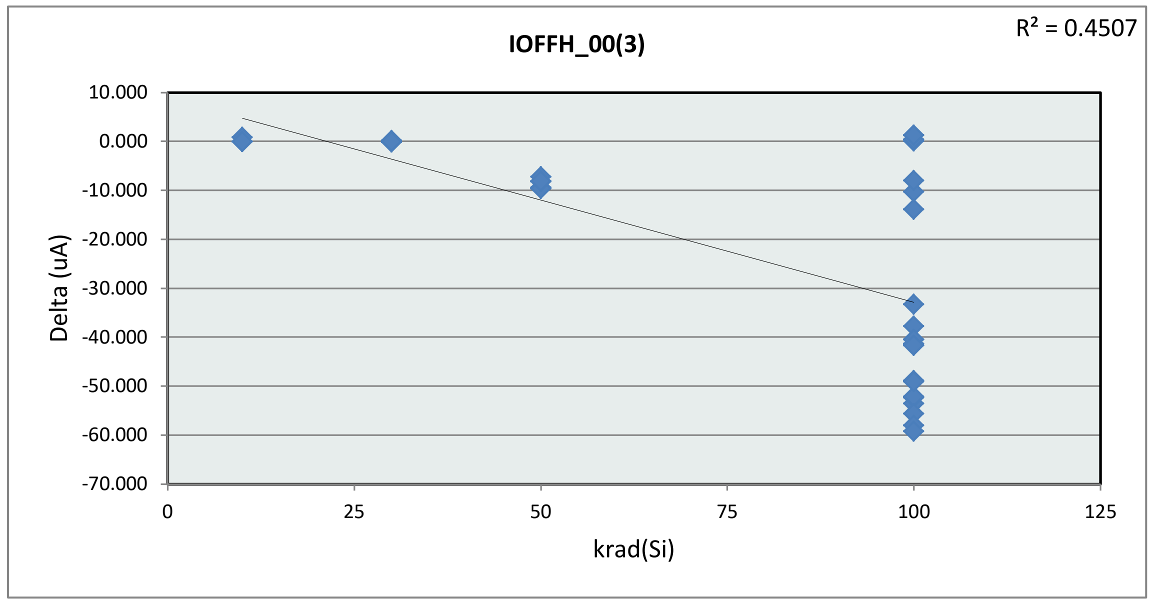


	IOFFH_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.182	0.766	4.541	0.016
Average	0.182	0.848	10.373	32.284
Max	0.182	0.933	13.560	57.188
UL	150.000	150.000	150.000	150.000

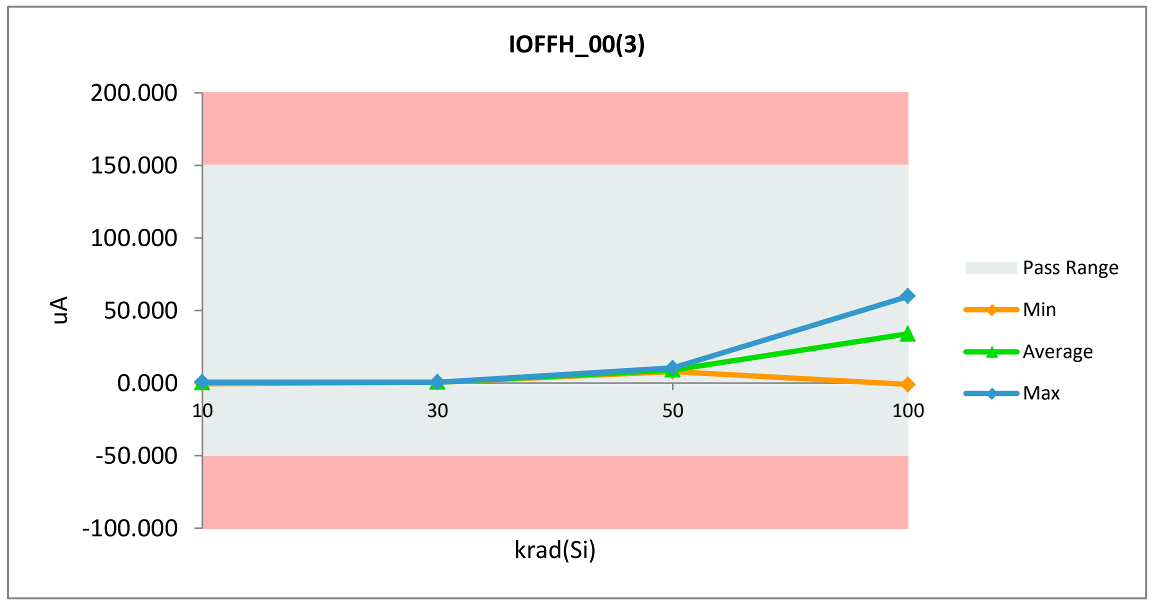


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.716	0.846	-0.129
10	2	0.415	-0.347	0.762
10	3	0.716	0.846	-0.129
10	4	0.716	0.846	-0.129
10	5	0.716	0.846	-0.129
30	1	0.749	0.847	-0.099
30	2	0.618	0.773	-0.155
30	3	0.655	0.773	-0.117
30	4	0.749	0.642	0.106
30	5	0.693	0.791	-0.099
50	11	0.693	8.003	-7.310
50	12	0.637	10.112	-9.475
50	13	0.767	10.413	-9.646
50	14	0.618	8.907	-8.289
50	15	0.767	8.907	-8.140
100	22	0.415	49.257	-48.842
100	23	0.415	54.028	-53.613
100	24	0.716	42.100	-41.384
100	25	0.716	11.087	-10.371
100	26	0.716	8.702	-7.986
100	27	0.415	0.352	0.063
100	28	0.415	-0.840	1.256
100	29	0.716	0.352	0.364
100	30	0.415	52.835	-52.420
100	31	0.716	38.522	-37.806
100	32	0.716	52.835	-52.119
100	33	0.415	33.750	-33.335
100	34	0.415	40.907	-40.492
100	35	0.415	40.907	-40.492
100	36	0.716	56.413	-55.697
100	37	0.716	14.666	-13.950
100	38	0.415	-0.840	1.256
100	39	0.716	58.799	-58.083
100	41	0.716	59.992	-59.276
100	42	0.415	42.100	-41.685
100	43	0.114	49.257	-49.143
100	44	0.415	42.100	-41.685
	Max	0.767	59.992	1.256
	Average	0.596	21.635	-21.038
	Min	0.114	-0.840	-59.276
	Std Dev	0.163	22.618	22.670

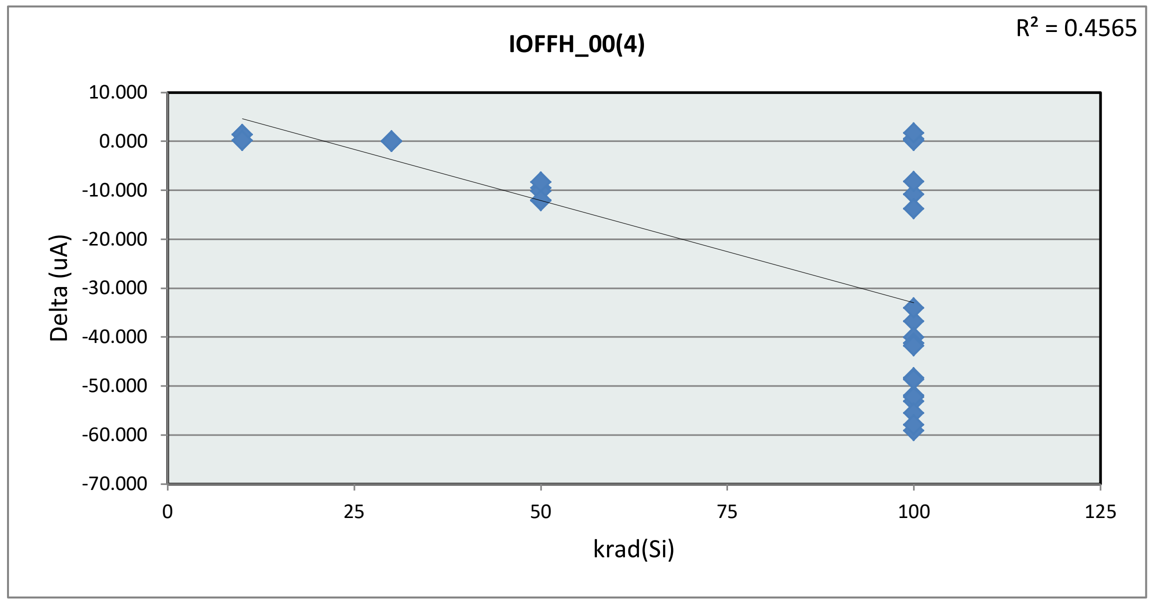


	IOFFH_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.347	0.642	8.003	-0.840
Average	0.607	0.765	9.268	33.967
Max	0.846	0.847	10.413	59.992
UL	150.000	150.000	150.000	150.000

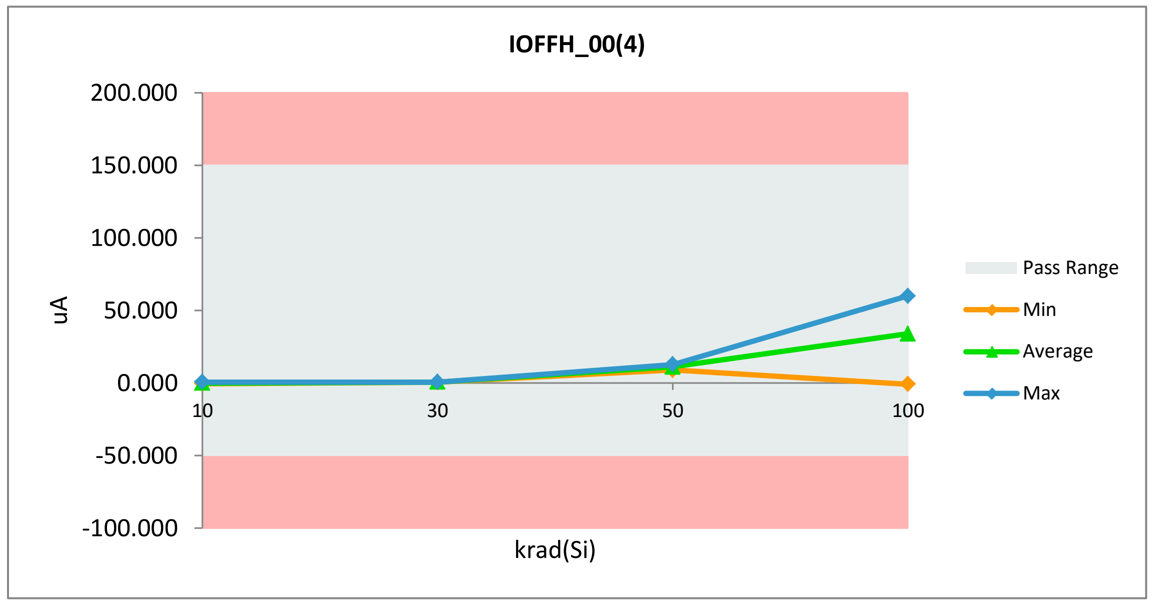


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.919	-0.403	1.322
10	2	0.919	0.787	0.132
10	3	0.919	-0.403	1.322
10	4	0.919	-0.403	1.322
10	5	0.919	0.787	0.132
30	1	0.651	0.676	-0.026
30	2	0.613	0.602	0.011
30	3	0.781	0.695	0.086
30	4	0.781	0.788	-0.007
30	5	0.632	0.714	-0.082
50	11	0.688	12.862	-12.174
50	12	0.632	10.161	-9.529
50	13	0.818	11.061	-10.243
50	14	0.576	8.960	-8.384
50	15	0.799	12.862	-12.063
100	22	0.919	49.305	-48.386
100	23	0.919	54.068	-53.149
100	24	0.919	42.159	-41.240
100	25	0.318	11.197	-10.879
100	26	0.619	8.815	-8.196
100	27	0.619	0.479	0.139
100	28	0.919	0.479	0.439
100	29	0.619	0.479	0.139
100	30	0.919	52.877	-51.958
100	31	0.619	37.396	-36.777
100	32	0.619	52.877	-52.258
100	33	0.919	35.014	-34.095
100	34	0.919	40.969	-40.050
100	35	0.919	40.969	-40.050
100	36	0.919	56.450	-55.531
100	37	0.919	14.770	-13.851
100	38	0.919	-0.711	1.630
100	39	0.919	60.022	-59.103
100	41	0.919	58.832	-57.913
100	42	0.919	42.159	-41.240
100	43	0.619	49.305	-48.686
100	44	0.318	42.159	-41.841
	Max	0.919	60.022	1.630
	Average	0.778	21.887	-21.109
	Min	0.318	-0.711	-59.103
	Std Dev	0.174	22.534	22.504

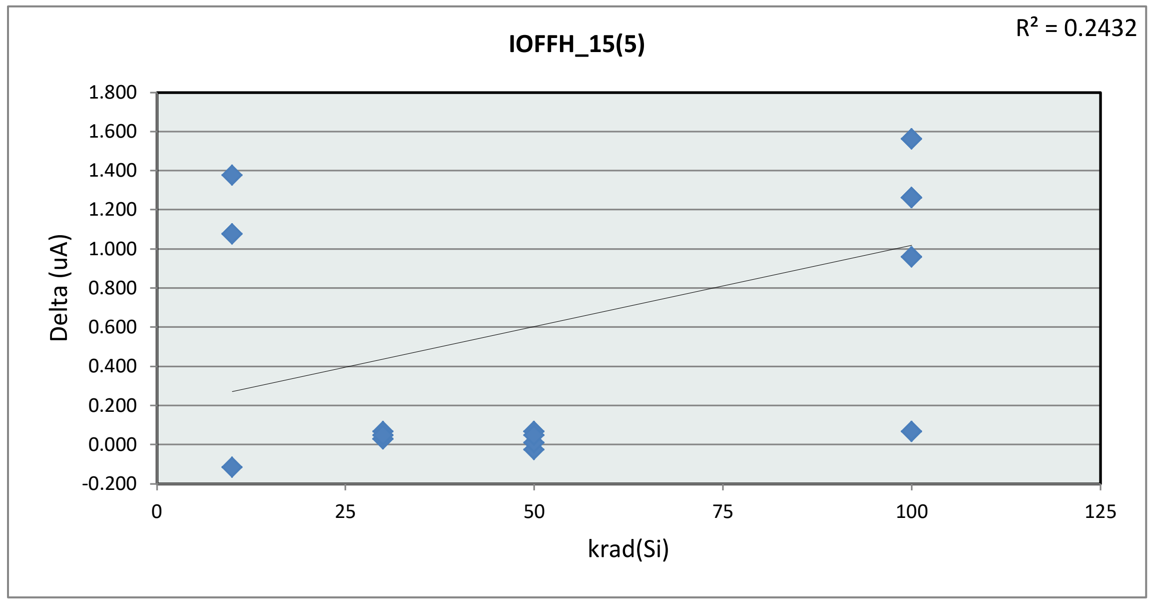


	IOFFH_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.403	0.602	8.960	-0.711
Average	0.073	0.695	11.181	34.094
Max	0.787	0.788	12.862	60.022
UL	150.000	150.000	150.000	150.000

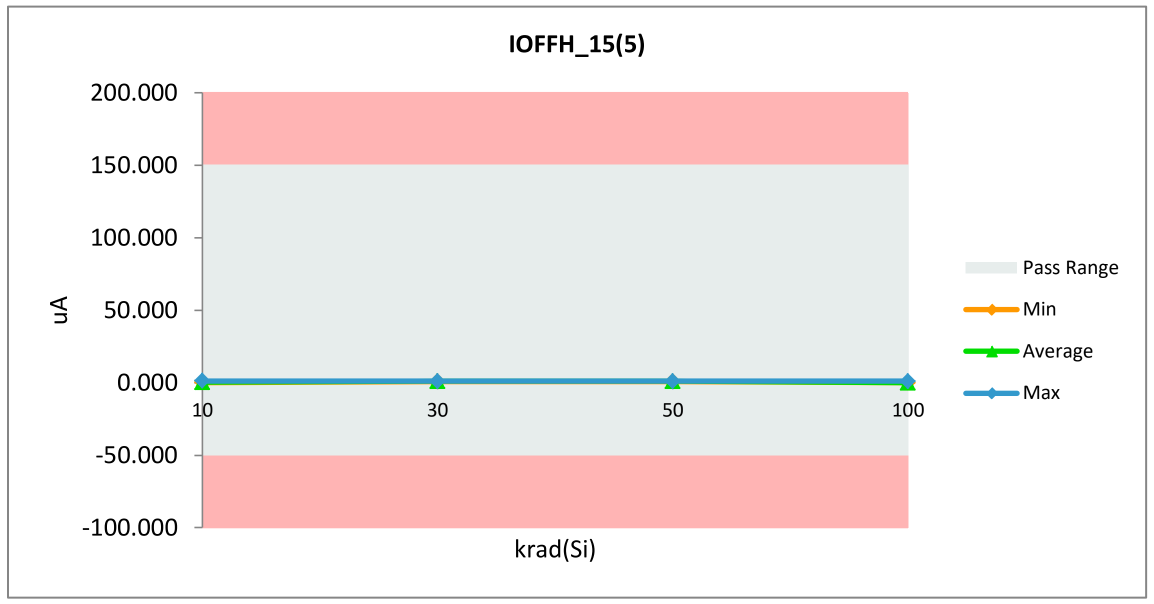


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_15(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.146	1.262	-0.116
10	2	1.146	0.071	1.075
10	3	1.446	0.071	1.375
10	4	1.146	0.071	1.075
10	5	1.146	0.071	1.075
30	1	1.026	0.997	0.029
30	2	1.008	0.942	0.066
30	3	1.045	1.016	0.029
30	4	1.026	0.997	0.029
30	5	1.045	0.997	0.048
50	11	0.989	1.016	-0.027
50	12	1.026	0.960	0.066
50	13	1.064	0.997	0.066
50	14	0.952	0.942	0.010
50	15	1.064	1.016	0.048
100	22	1.146	-0.114	1.260
100	23	1.146	1.078	0.068
100	24	1.446	-0.114	1.560
100	25	1.146	-0.114	1.260
100	26	1.146	-0.114	1.260
100	27	0.845	-0.114	0.959
100	28	1.146	-0.114	1.260
100	29	0.845	-0.114	0.959
100	30	0.845	-0.114	0.959
100	31	0.845	-0.114	0.959
100	32	1.146	-0.114	1.260
100	33	1.146	-0.114	1.260
100	34	1.146	-0.114	1.260
100	35	1.146	-0.114	1.260
100	36	1.146	-0.114	1.260
100	37	1.146	-0.114	1.260
100	38	1.146	-0.114	1.260
100	39	1.446	-0.114	1.560
100	41	1.446	-0.114	1.560
100	42	1.146	1.078	0.068
100	43	1.446	-0.114	1.560
100	44	1.146	1.078	0.068
	Max	1.446	1.262	1.560
	Average	1.121	0.338	0.784
	Min	0.845	-0.114	-0.116
	Std Dev	0.162	0.550	0.614

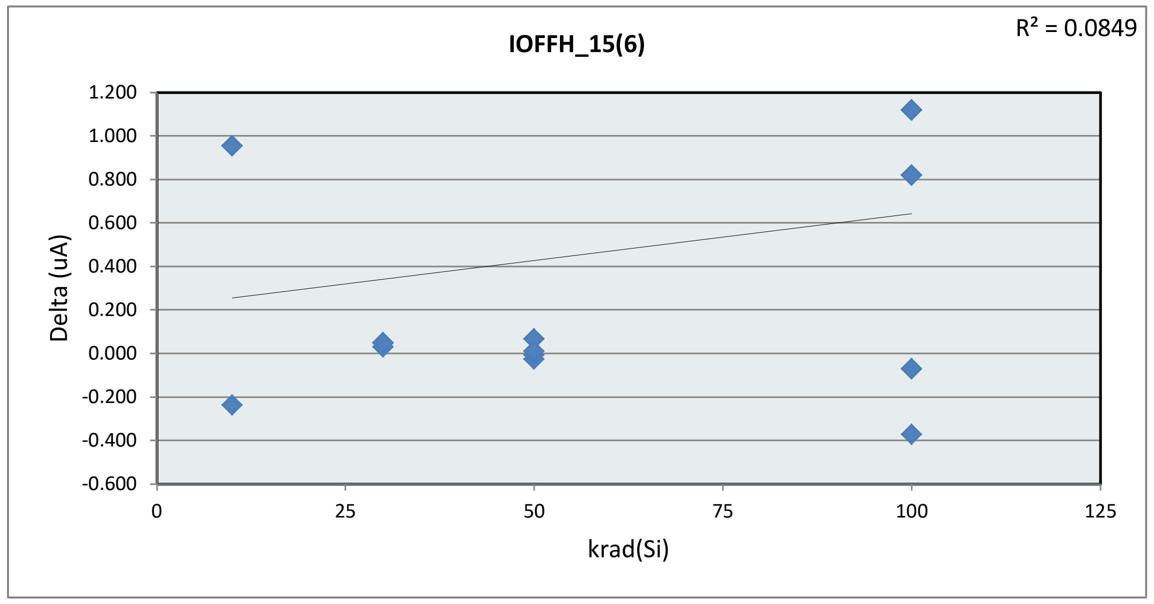


	IOFFH_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.071	0.942	0.942	-0.114
Average	0.309	0.990	0.986	0.048
Max	1.262	1.016	1.016	1.078
UL	150.000	150.000	150.000	150.000

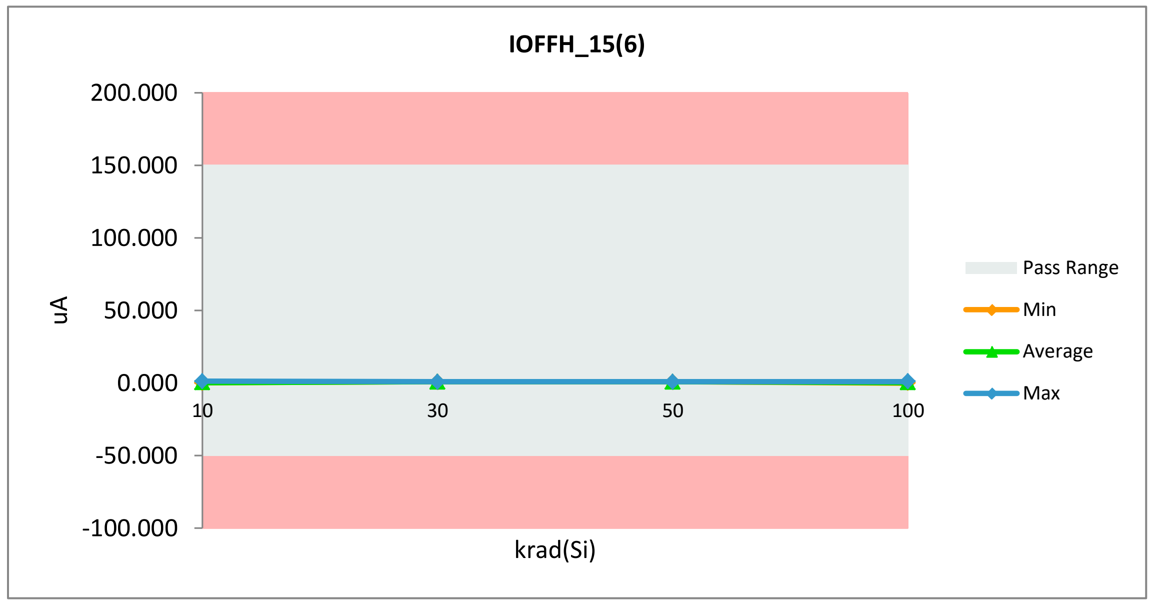


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_15(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.135	0.182	0.953
10	2	1.135	1.373	-0.238
10	3	1.135	0.182	0.953
10	4	1.135	0.182	0.953
10	5	1.135	0.182	0.953
30	1	1.037	0.989	0.048
30	2	0.981	0.952	0.029
30	3	1.056	1.008	0.048
30	4	1.018	0.989	0.029
30	5	1.037	0.989	0.048
50	11	0.981	1.008	-0.027
50	12	1.018	0.952	0.067
50	13	1.056	0.989	0.067
50	14	0.944	0.952	-0.008
50	15	1.037	1.026	0.011
100	22	0.835	0.016	0.818
100	23	1.135	0.016	1.119
100	24	0.835	0.016	0.818
100	25	1.135	0.016	1.119
100	26	1.135	1.207	-0.072
100	27	1.135	0.016	1.119
100	28	1.135	1.207	-0.072
100	29	0.835	0.016	0.818
100	30	1.135	0.016	1.119
100	31	1.135	0.016	1.119
100	32	0.835	0.016	0.818
100	33	1.135	0.016	1.119
100	34	1.135	0.016	1.119
100	35	1.135	0.016	1.119
100	36	1.135	1.207	-0.072
100	37	0.835	0.016	0.818
100	38	1.135	0.016	1.119
100	39	1.135	1.207	-0.072
100	41	0.835	1.207	-0.372
100	42	1.135	1.207	-0.072
100	43	1.135	0.016	1.119
100	44	0.835	0.016	0.818
	Max	1.135	1.373	1.119
	Average	1.046	0.526	0.520
	Min	0.835	0.016	-0.372
	Std Dev	0.117	0.533	0.537



	IOFFH_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.182	0.952	0.952	0.016
Average	0.421	0.985	0.985	0.341
Max	1.373	1.008	1.026	1.207
UL	150.000	150.000	150.000	150.000



HDR Biased TID Report
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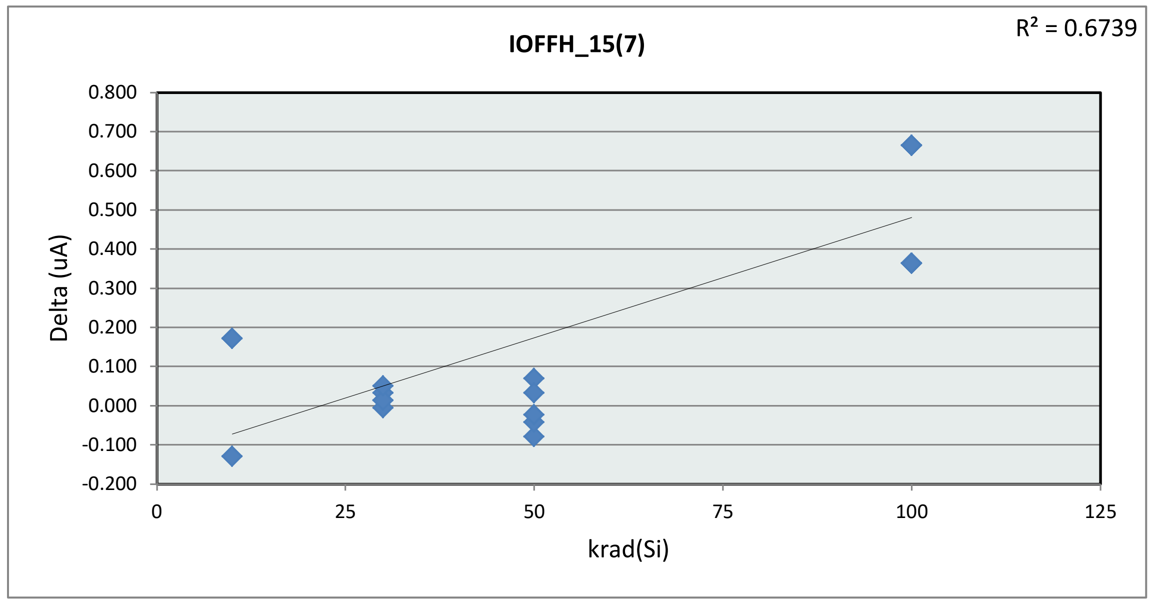
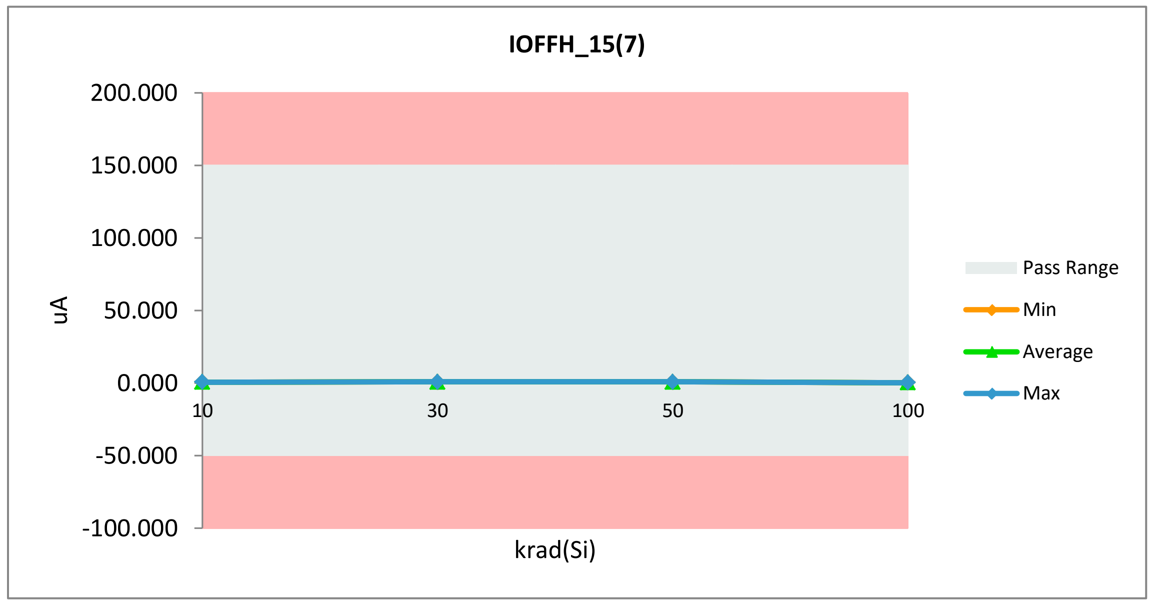
	IOFFH_15(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.017	0.846	0.171
10	2	1.017	0.846	0.171
10	3	1.017	0.846	0.171
10	4	0.716	0.846	-0.129
10	5	0.716	0.846	-0.129
30	1	1.010	0.978	0.032
30	2	0.954	0.941	0.013
30	3	0.991	0.996	-0.005
30	4	0.991	0.978	0.013
30	5	1.010	0.959	0.051
50	11	0.935	1.015	-0.080
50	12	0.991	0.922	0.069
50	13	1.029	0.996	0.032
50	14	0.898	0.941	-0.043
50	15	0.991	1.015	-0.024
100	22	0.716	0.352	0.364
100	23	0.716	0.352	0.364
100	24	0.716	0.352	0.364
100	25	1.017	0.352	0.665
100	26	0.716	0.352	0.364
100	27	0.716	0.352	0.364
100	28	0.716	0.352	0.364
100	29	1.017	0.352	0.665
100	30	1.017	0.352	0.665
100	31	1.017	0.352	0.665
100	32	0.716	0.352	0.364
100	33	0.716	0.352	0.364
100	34	0.716	0.352	0.364
100	35	1.017	0.352	0.665
100	36	1.017	0.352	0.665
100	37	0.716	0.352	0.364
100	38	0.716	0.352	0.364
100	39	1.017	0.352	0.665
100	41	1.017	0.352	0.665
100	42	0.716	0.352	0.364
100	43	1.017	0.352	0.665
100	44	1.017	0.352	0.665
	Max	1.029	1.015	0.665
	Average	0.893	0.587	0.306
	Min	0.716	0.352	-0.129
	Std Dev	0.142	0.291	0.273



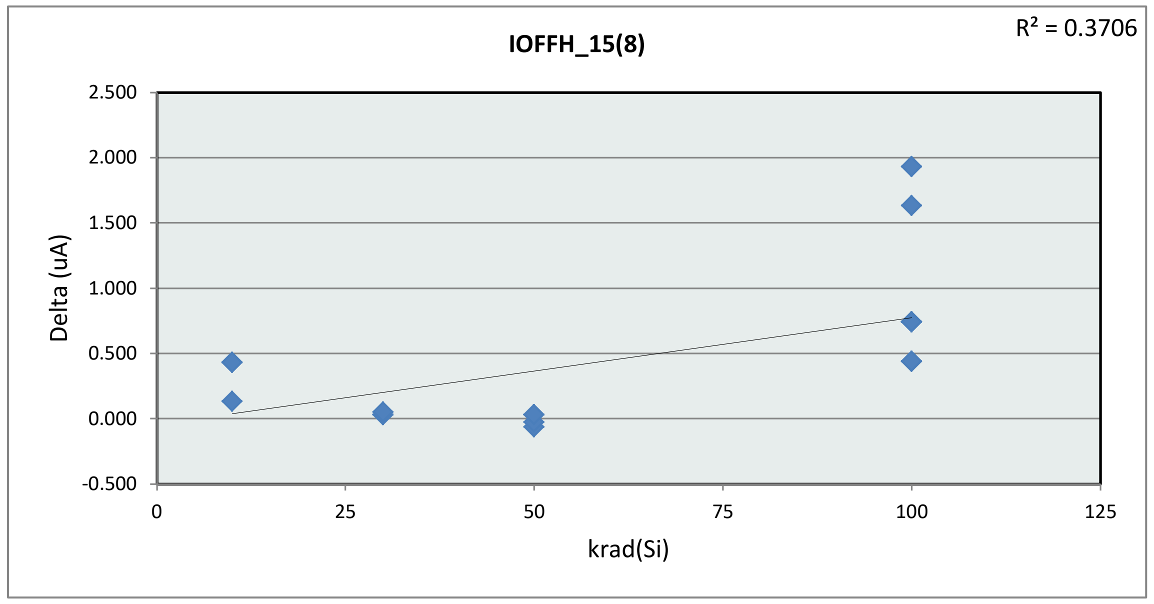
	IOFFH_15(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	uA
Min Limit	-50	uA

krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.846	0.941	0.922	0.352
Average	0.846	0.970	0.978	0.352
Max	0.846	0.996	1.015	0.352
UL	150.000	150.000	150.000	150.000

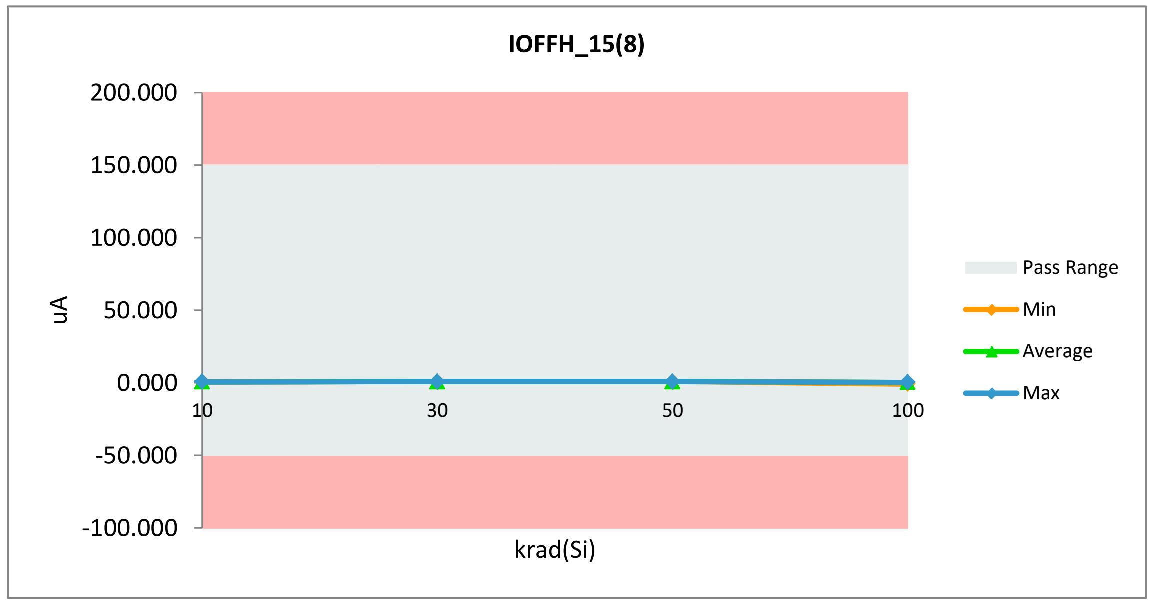


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_15(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	1.219	0.787	0.432
10	2	1.219	0.787	0.432
10	3	0.919	0.787	0.132
10	4	1.219	0.787	0.432
10	5	1.219	0.787	0.432
30	1	1.041	1.011	0.030
30	2	0.985	0.955	0.030
30	3	1.023	0.993	0.030
30	4	1.023	0.993	0.030
30	5	1.041	0.993	0.049
50	11	0.967	1.030	-0.063
50	12	1.004	0.974	0.030
50	13	1.041	1.011	0.030
50	14	0.930	0.955	-0.026
50	15	1.023	0.993	0.030
100	22	1.219	0.479	0.740
100	23	0.919	0.479	0.439
100	24	1.219	-0.711	1.930
100	25	0.919	0.479	0.439
100	26	1.219	0.479	0.740
100	27	0.919	0.479	0.439
100	28	1.219	-0.711	1.930
100	29	1.219	0.479	0.740
100	30	1.219	0.479	0.740
100	31	0.919	0.479	0.439
100	32	1.219	0.479	0.740
100	33	0.919	0.479	0.439
100	34	1.219	0.479	0.740
100	35	1.219	0.479	0.740
100	36	1.219	0.479	0.740
100	37	1.219	0.479	0.740
100	38	0.919	-0.711	1.630
100	39	1.219	0.479	0.740
100	41	1.219	0.479	0.740
100	42	1.219	0.479	0.740
100	43	1.219	0.479	0.740
100	44	1.219	0.479	0.740
	Max	1.219	1.030	1.930
	Average	1.105	0.563	0.543
	Min	0.919	-0.711	-0.063
	Std Dev	0.130	0.444	0.489

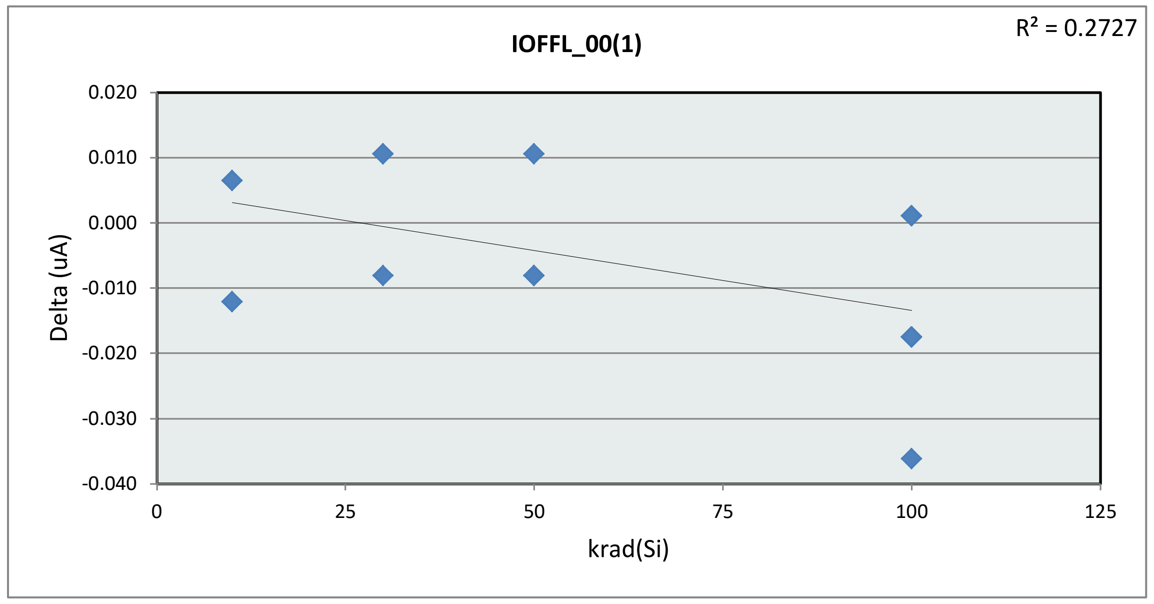


	IOFFH_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.787	0.955	0.955	-0.711
Average	0.787	0.989	0.993	0.317
Max	0.787	1.011	1.030	0.479
UL	150.000	150.000	150.000	150.000

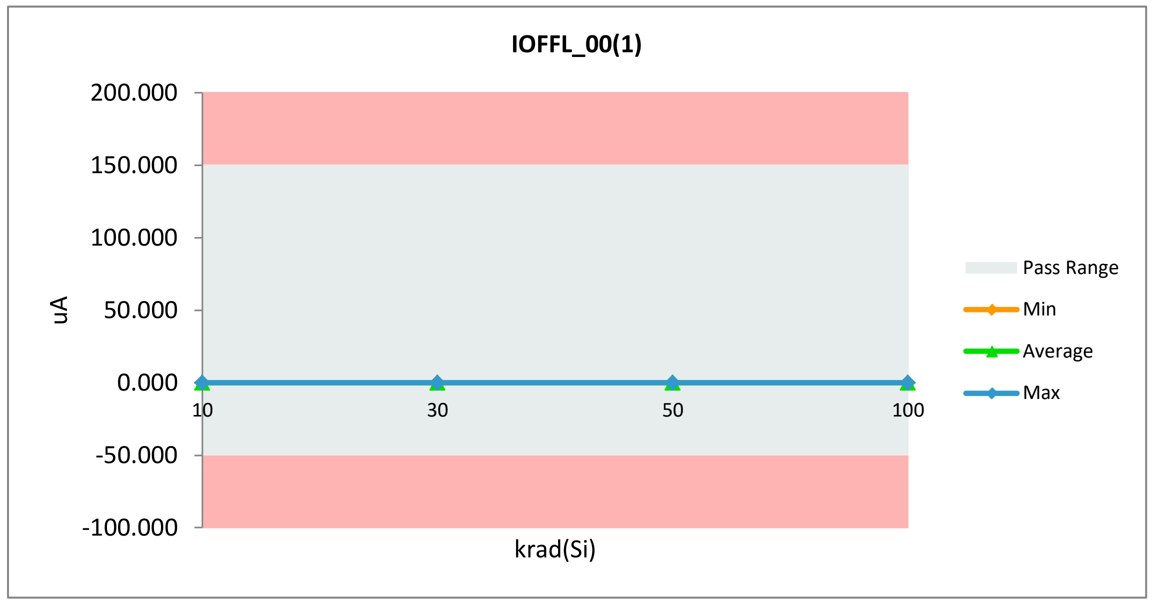


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_00(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.028	-0.016	-0.012
10	2	-0.010	-0.016	0.006
10	3	-0.028	-0.016	-0.012
10	4	-0.010	-0.016	0.006
10	5	-0.028	-0.016	-0.012
30	1	0.003	0.011	-0.008
30	2	0.003	-0.007	0.011
30	3	0.003	-0.007	0.011
30	4	0.003	-0.007	0.011
30	5	0.003	-0.007	0.011
50	11	0.003	0.011	-0.008
50	12	0.003	-0.007	0.011
50	13	0.003	0.011	-0.008
50	14	0.003	0.011	-0.008
50	15	0.003	-0.007	0.011
100	22	-0.028	0.008	-0.036
100	23	-0.028	-0.011	-0.018
100	24	-0.028	-0.011	-0.018
100	25	-0.028	-0.011	-0.018
100	26	-0.028	-0.011	-0.018
100	27	-0.010	-0.011	0.001
100	28	-0.028	-0.011	-0.018
100	29	-0.010	-0.011	0.001
100	30	-0.028	-0.011	-0.018
100	31	-0.028	-0.011	-0.018
100	32	-0.010	-0.011	0.001
100	33	-0.010	-0.011	0.001
100	34	-0.028	-0.011	-0.018
100	35	-0.028	-0.011	-0.018
100	36	-0.010	-0.011	0.001
100	37	-0.028	-0.011	-0.018
100	38	-0.028	-0.011	-0.018
100	39	-0.028	-0.011	-0.018
100	41	-0.028	-0.011	-0.018
100	42	-0.028	-0.011	-0.018
100	43	-0.028	0.008	-0.036
100	44	-0.028	-0.029	0.001
	Max	0.003	0.011	0.011
	Average	-0.016	-0.008	-0.008
	Min	-0.028	-0.029	-0.036
	Std Dev	0.014	0.009	0.013

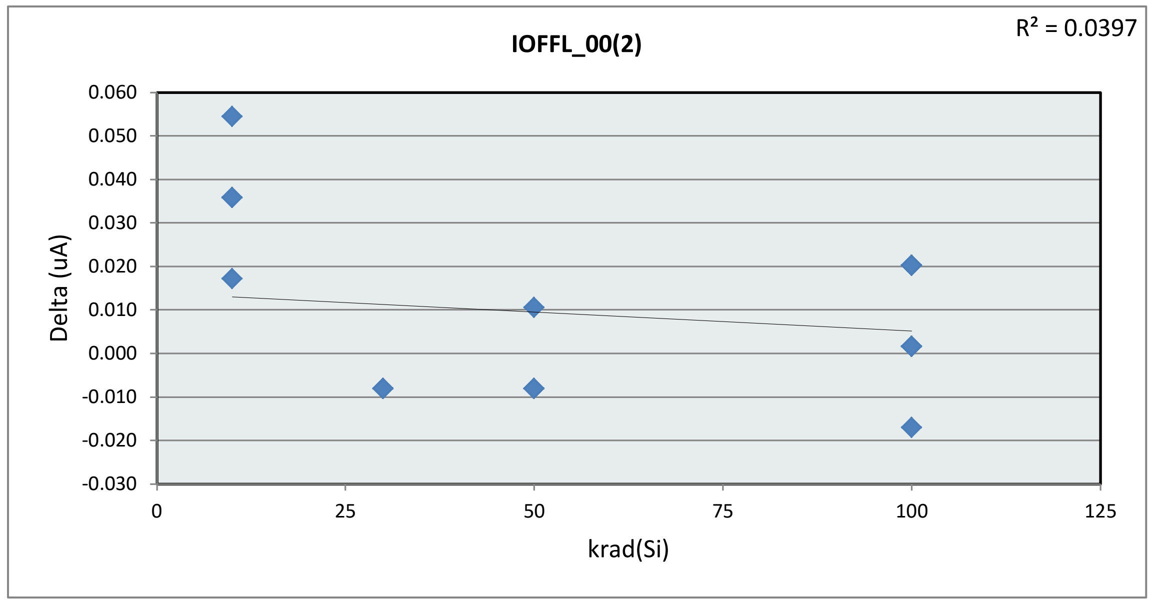


	IOFFL_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.016	-0.007	-0.007	-0.029
Average	-0.016	-0.003	0.004	-0.010
Max	-0.016	0.011	0.011	0.008
UL	150.000	150.000	150.000	150.000

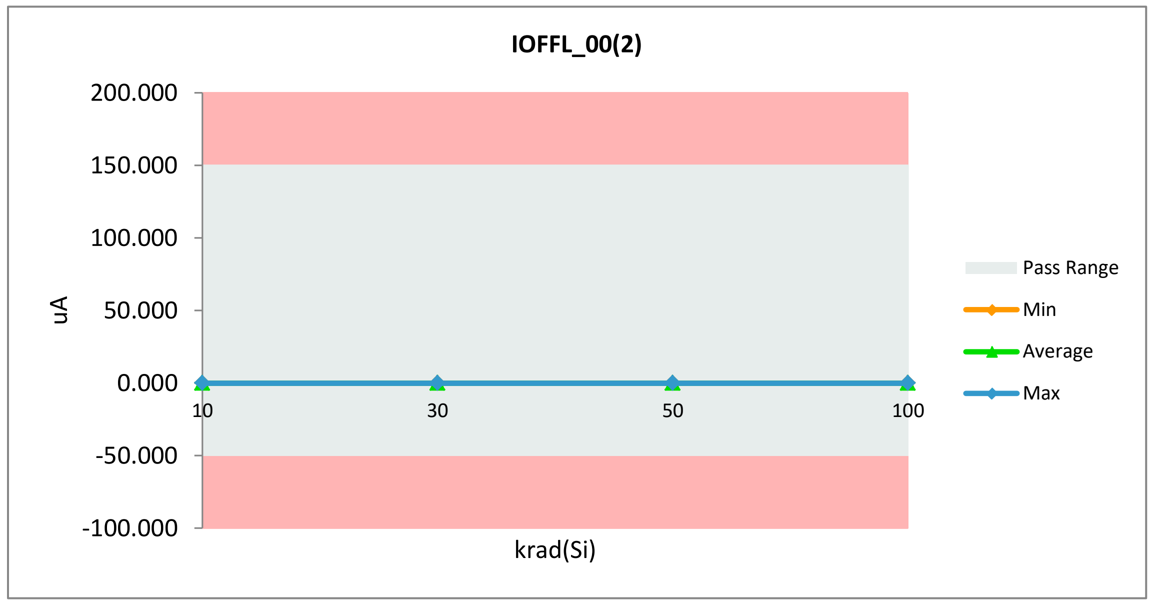


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.010	-0.046	0.036
10	2	-0.010	-0.027	0.017
10	3	0.008	-0.046	0.054
10	4	-0.010	-0.046	0.036
10	5	-0.010	-0.046	0.036
30	1	-0.005	0.003	-0.008
30	2	-0.005	0.003	-0.008
30	3	-0.005	0.003	-0.008
30	4	-0.005	0.003	-0.008
30	5	-0.005	0.003	-0.008
50	11	-0.005	0.003	-0.008
50	12	-0.005	0.003	-0.008
50	13	-0.005	0.003	-0.008
50	14	-0.005	0.003	-0.008
50	15	0.013	0.003	0.011
100	22	0.008	-0.012	0.020
100	23	-0.010	-0.012	0.002
100	24	-0.010	-0.012	0.002
100	25	-0.010	-0.012	0.002
100	26	0.008	-0.012	0.020
100	27	-0.010	0.007	-0.017
100	28	-0.010	-0.012	0.002
100	29	-0.010	-0.012	0.002
100	30	0.008	-0.012	0.020
100	31	-0.010	-0.012	0.002
100	32	0.008	-0.012	0.020
100	33	-0.010	-0.012	0.002
100	34	-0.010	-0.012	0.002
100	35	-0.010	-0.012	0.002
100	36	0.008	-0.012	0.020
100	37	-0.010	-0.012	0.002
100	38	0.008	-0.012	0.020
100	39	0.008	-0.012	0.020
100	41	0.008	-0.012	0.020
100	42	-0.010	-0.012	0.002
100	43	-0.010	-0.012	0.002
100	44	-0.010	-0.012	0.002
	Max	0.013	0.007	0.054
	Average	-0.004	-0.012	0.008
	Min	-0.010	-0.046	-0.017
	Std Dev	0.008	0.014	0.016



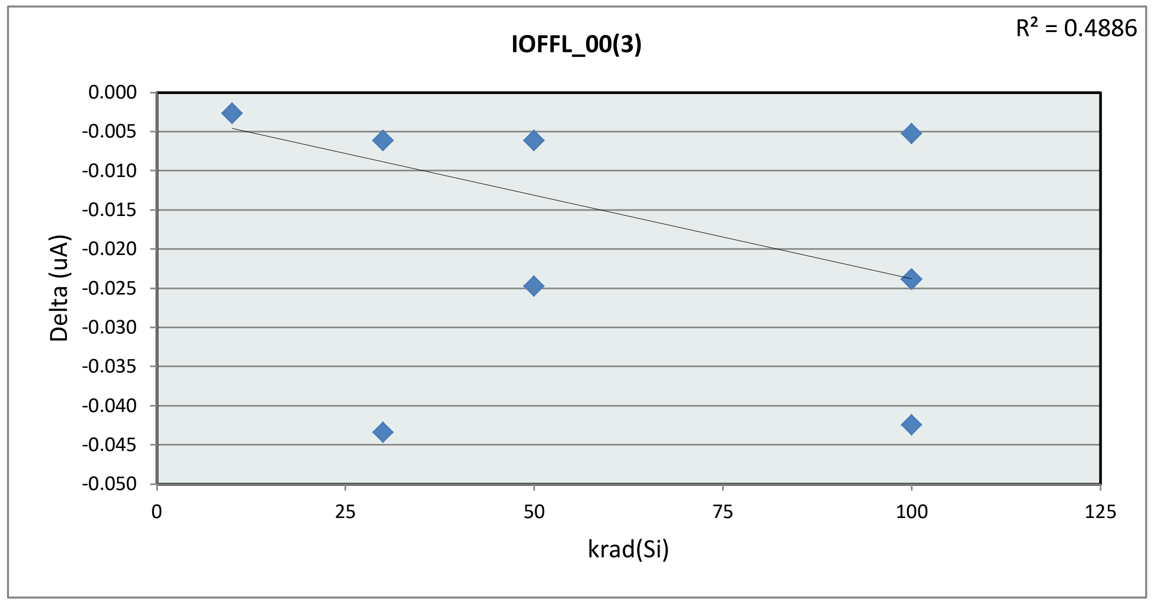
	IOFFL_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.046	0.003	0.003	-0.012
Average	-0.042	0.003	0.003	-0.011
Max	-0.027	0.003	0.003	0.007
UL	150.000	150.000	150.000	150.000



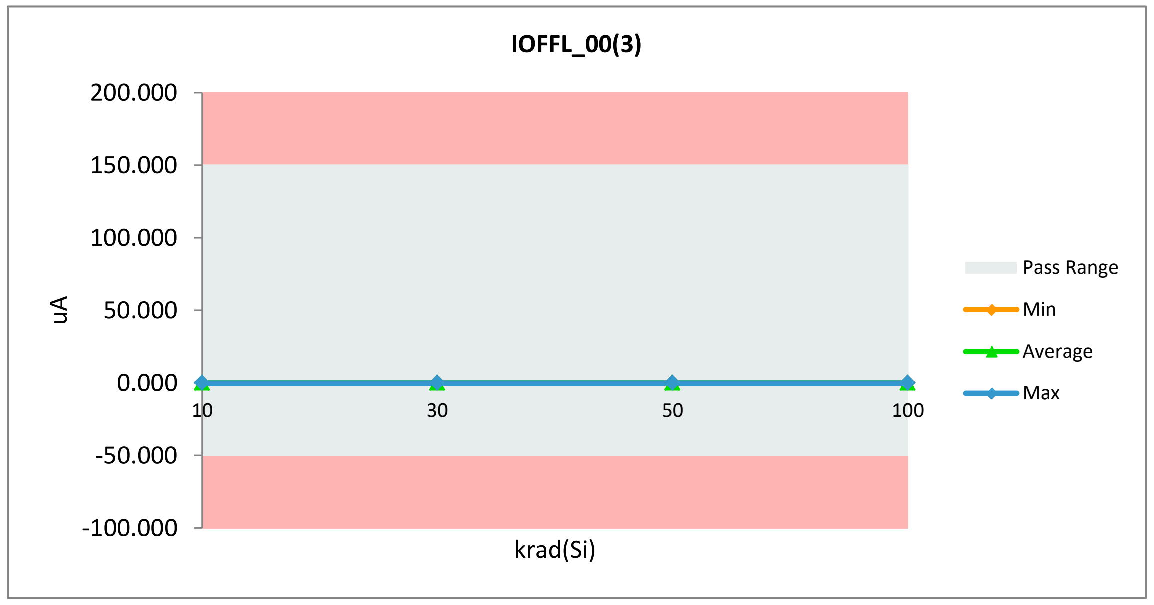
HDR Biased TID Report
SN55LVCP22A-SP

	IOFFL_00(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.002	0.001	-0.003
10	2	-0.002	0.001	-0.003
10	3	-0.002	0.001	-0.003
10	4	-0.002	0.001	-0.003
10	5	-0.002	0.001	-0.003
30	1	-0.035	0.009	-0.043
30	2	-0.016	-0.010	-0.006
30	3	-0.016	-0.010	-0.006
30	4	-0.016	-0.010	-0.006
30	5	-0.016	-0.010	-0.006
50	11	-0.016	-0.010	-0.006
50	12	-0.016	0.009	-0.025
50	13	-0.016	-0.010	-0.006
50	14	-0.016	-0.010	-0.006
50	15	-0.016	-0.010	-0.006
100	22	-0.002	0.022	-0.024
100	23	-0.002	0.022	-0.024
100	24	-0.002	0.022	-0.024
100	25	-0.002	0.022	-0.024
100	26	-0.002	0.022	-0.024
100	27	-0.002	0.022	-0.024
100	28	-0.002	0.022	-0.024
100	29	-0.021	0.022	-0.042
100	30	-0.002	0.022	-0.024
100	31	-0.002	0.022	-0.024
100	32	-0.002	0.003	-0.005
100	33	-0.002	0.022	-0.024
100	34	-0.002	0.022	-0.024
100	35	-0.002	0.022	-0.024
100	36	-0.002	0.022	-0.024
100	37	-0.002	0.022	-0.024
100	38	-0.002	0.022	-0.024
100	39	-0.002	0.022	-0.024
100	41	-0.002	0.022	-0.024
100	42	-0.002	0.022	-0.024
100	43	-0.002	0.022	-0.024
100	44	-0.002	0.022	-0.024
	Max	-0.002	0.022	-0.003
	Average	-0.007	0.011	-0.018
	Min	-0.035	-0.010	-0.043
	Std Dev	0.008	0.014	0.011

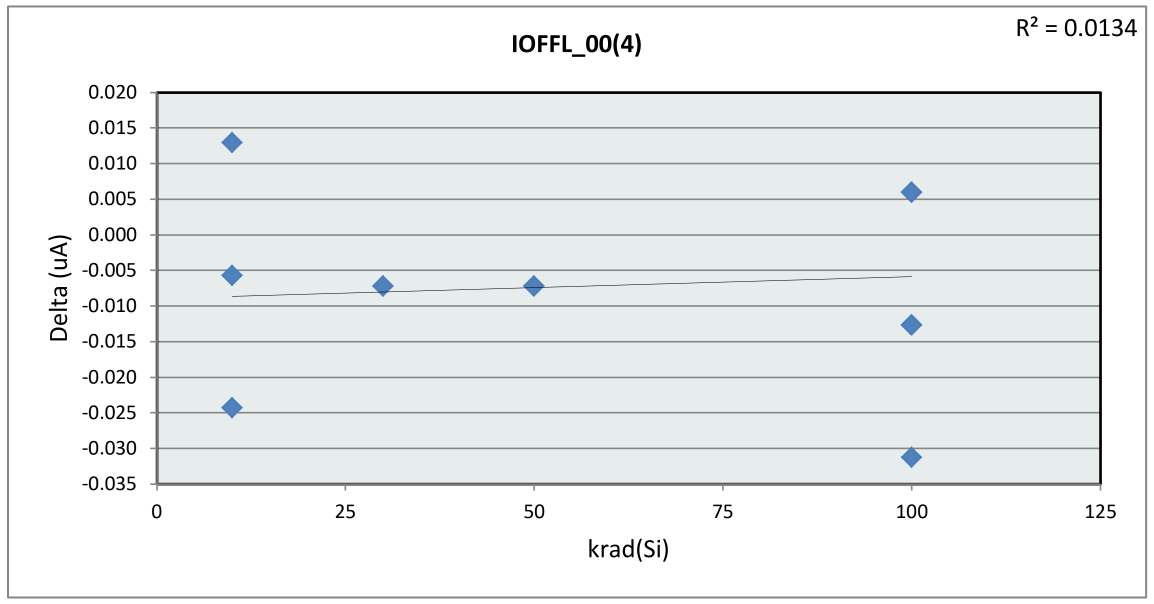


	IOFFL_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.001	-0.010	-0.010	0.003
Average	0.001	-0.006	-0.006	0.021
Max	0.001	0.009	0.009	0.022
UL	150.000	150.000	150.000	150.000

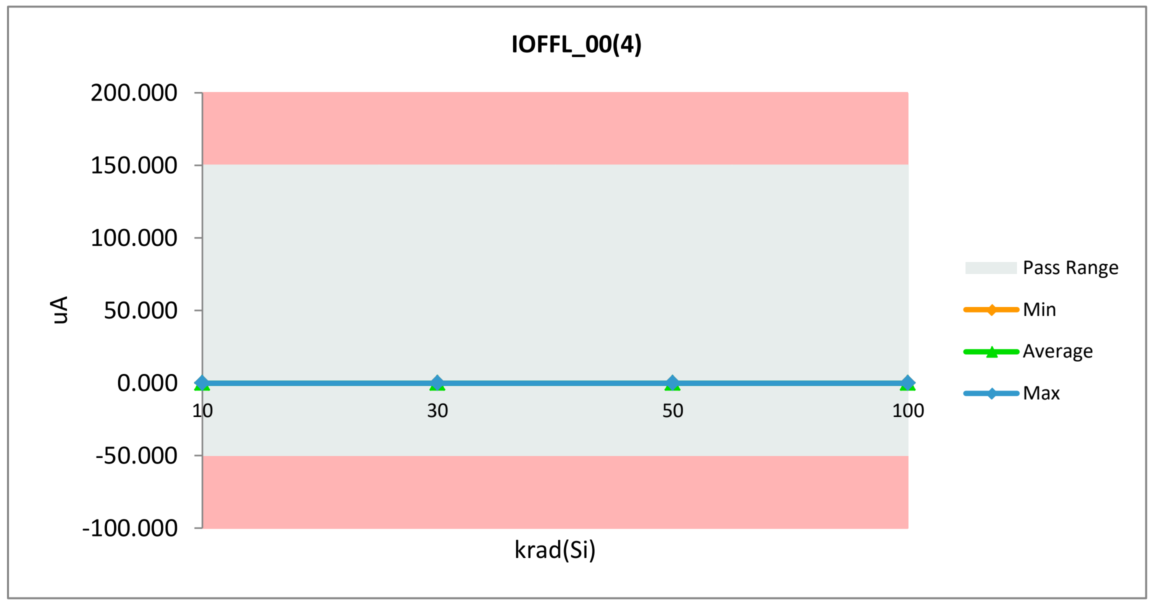


HDR Biased TID Report
SN55LVCP22A-SP

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
		IOFFL_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
10	1	-0.026	-0.001	-0.024
10	2	-0.026	-0.001	-0.024
10	3	-0.007	-0.020	0.013
10	4	-0.007	-0.001	-0.006
10	5	-0.007	-0.001	-0.006
30	1	-0.019	-0.012	-0.007
30	2	-0.019	-0.012	-0.007
30	3	-0.019	-0.012	-0.007
30	4	-0.019	-0.012	-0.007
30	5	-0.019	-0.012	-0.007
50	11	-0.019	-0.012	-0.007
50	12	-0.019	-0.012	-0.007
50	13	-0.019	-0.012	-0.007
50	14	-0.019	-0.012	-0.007
50	15	-0.019	-0.012	-0.007
100	22	-0.007	0.005	-0.013
100	23	-0.007	-0.013	0.006
100	24	-0.026	-0.013	-0.013
100	25	-0.007	0.005	-0.013
100	26	-0.026	-0.013	-0.013
100	27	-0.007	-0.013	0.006
100	28	-0.007	-0.013	0.006
100	29	-0.007	0.005	-0.013
100	30	-0.007	-0.013	0.006
100	31	-0.007	-0.013	0.006
100	32	-0.007	0.005	-0.013
100	33	-0.007	0.005	-0.013
100	34	-0.026	-0.013	-0.013
100	35	-0.007	0.005	-0.013
100	36	-0.026	-0.013	-0.013
100	37	-0.026	0.005	-0.031
100	38	-0.007	0.005	-0.013
100	39	-0.007	-0.013	0.006
100	41	-0.007	-0.013	0.006
100	42	-0.007	-0.013	0.006
100	43	-0.007	-0.013	0.006
100	44	-0.007	0.005	-0.013
	Max	-0.007	0.005	0.013
	Average	-0.014	-0.007	-0.007
	Min	-0.026	-0.020	-0.031
	Std Dev	0.008	0.008	0.010



	IOFFL_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.020	-0.012	-0.012	-0.013
Average	-0.005	-0.012	-0.012	-0.006
Max	-0.001	-0.012	-0.012	0.005
UL	150.000	150.000	150.000	150.000



HDR Biased TID Report
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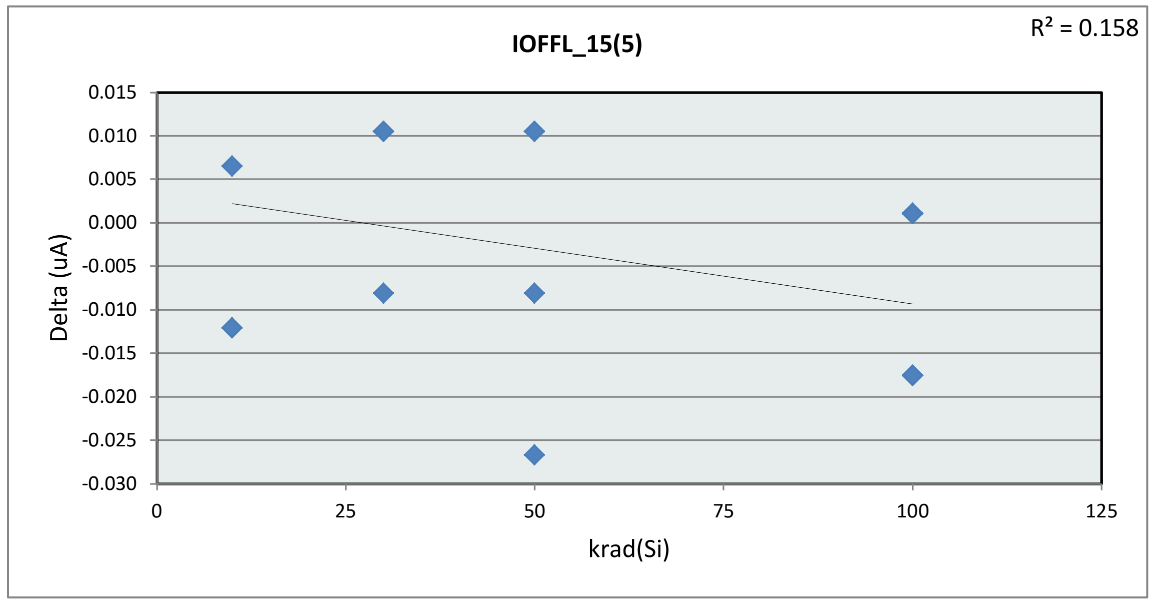
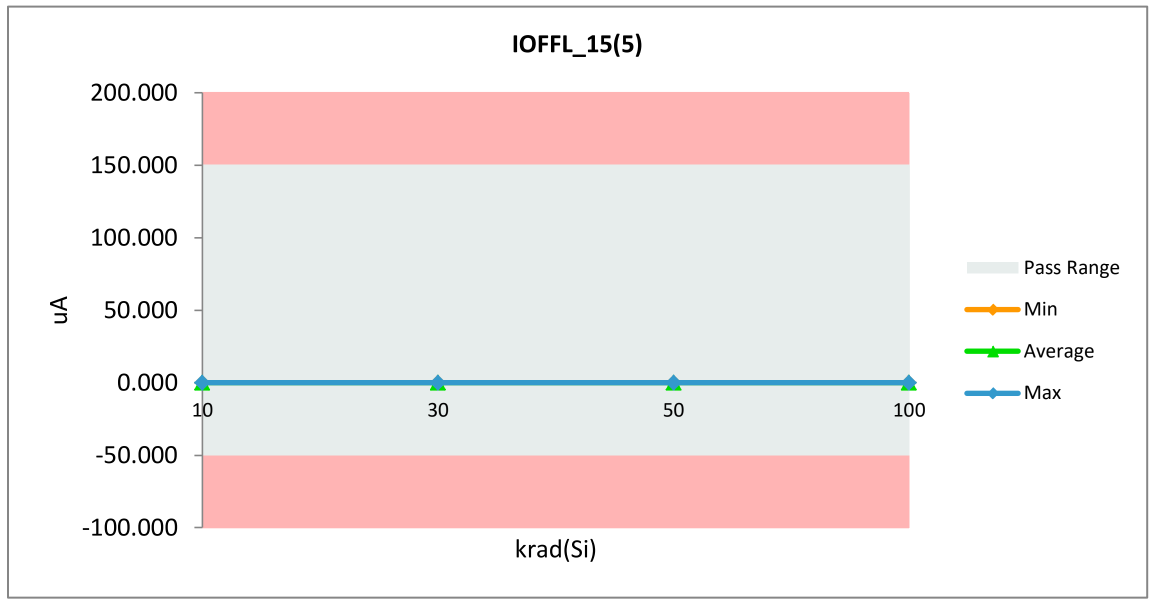
		IOFFL_15(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.028	-0.016	-0.012
10	2	-0.028	-0.016	-0.012
10	3	-0.010	-0.016	0.006
10	4	-0.010	-0.016	0.006
10	5	-0.028	-0.016	-0.012
30	1	0.003	-0.007	0.011
30	2	0.003	-0.007	0.011
30	3	0.003	-0.007	0.011
30	4	0.003	0.011	-0.008
30	5	0.003	-0.007	0.011
50	11	0.003	-0.007	0.011
50	12	0.003	0.011	-0.008
50	13	0.003	-0.007	0.011
50	14	-0.015	0.011	-0.027
50	15	0.003	-0.007	0.011
100	22	-0.028	-0.011	-0.018
100	23	-0.028	-0.011	-0.018
100	24	-0.028	-0.011	-0.018
100	25	-0.010	-0.011	0.001
100	26	-0.028	-0.011	-0.018
100	27	-0.010	-0.011	0.001
100	28	-0.028	-0.011	-0.018
100	29	-0.028	-0.011	-0.018
100	30	-0.028	-0.011	-0.018
100	31	-0.010	-0.011	0.001
100	32	-0.028	-0.011	-0.018
100	33	-0.010	-0.011	0.001
100	34	-0.028	-0.011	-0.018
100	35	-0.028	-0.011	-0.018
100	36	-0.010	-0.011	0.001
100	37	-0.010	-0.011	0.001
100	38	-0.028	-0.011	-0.018
100	39	-0.010	-0.011	0.001
100	41	-0.028	-0.011	-0.018
100	42	-0.028	-0.029	0.001
100	43	-0.010	-0.011	0.001
100	44	-0.028	-0.011	-0.018
	Max	0.003	0.011	0.011
	Average	-0.015	-0.009	-0.006
	Min	-0.028	-0.029	-0.027
	Std Dev	0.013	0.007	0.012



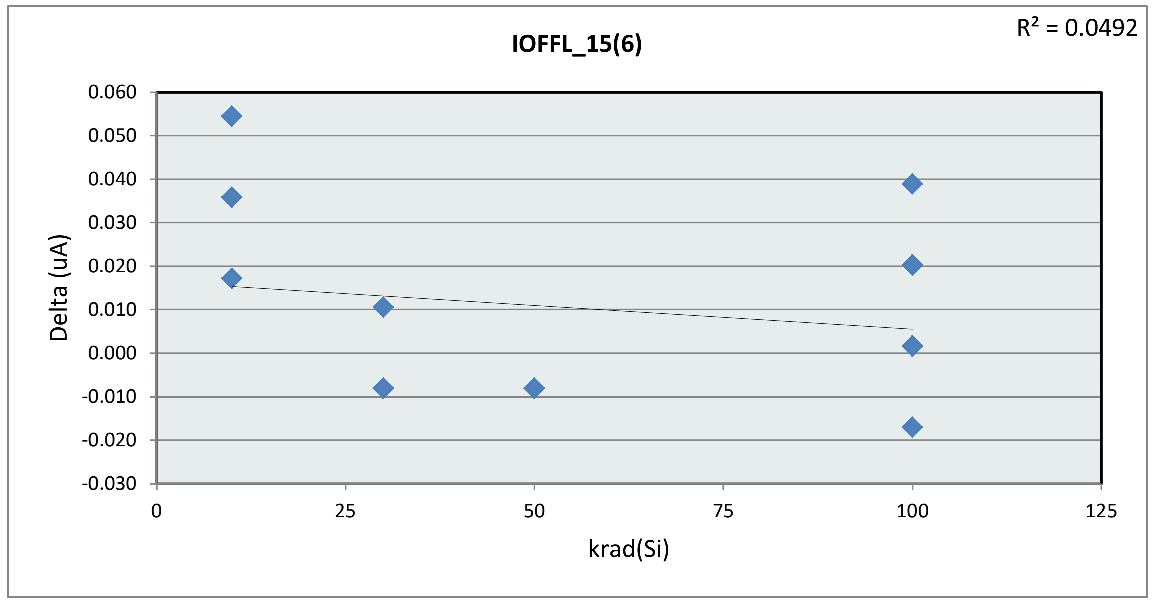
	IOFFL_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.016	-0.007	-0.007	-0.029
Average	-0.016	-0.003	0.000	-0.011
Max	-0.016	0.011	0.011	-0.011
UL	150.000	150.000	150.000	150.000



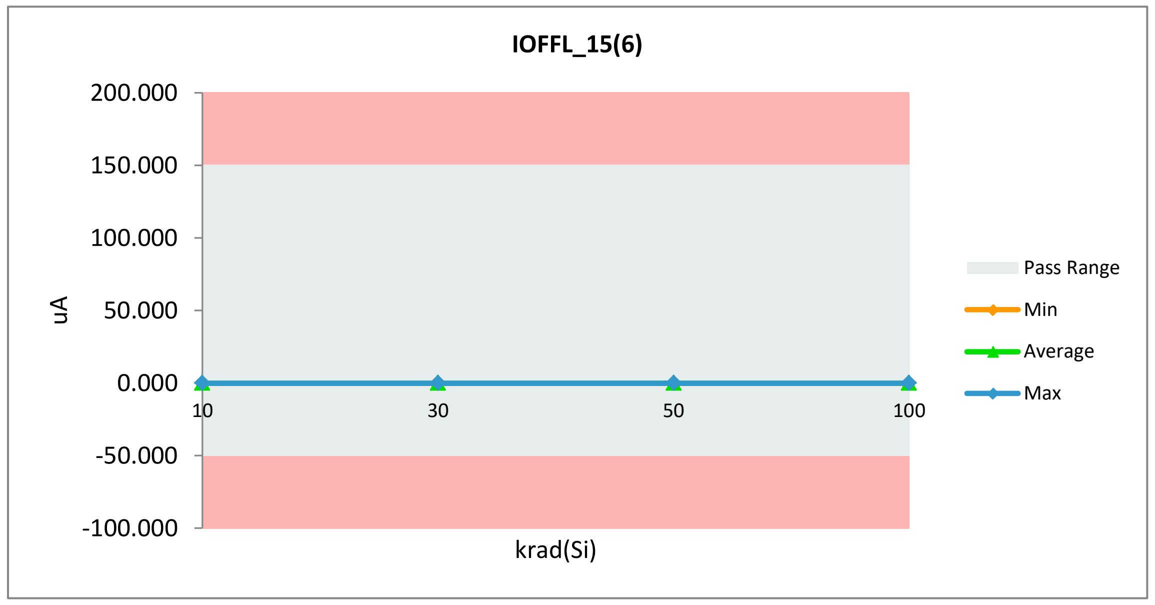
HDR Biased TID Report
SN55LVCP22A-SP

	IOFFL_15(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.010	-0.046	0.036
10	2	0.008	-0.046	0.054
10	3	0.008	-0.046	0.054
10	4	-0.010	-0.046	0.036
10	5	-0.010	-0.027	0.017
30	1	-0.005	0.003	-0.008
30	2	-0.005	0.003	-0.008
30	3	-0.005	0.003	-0.008
30	4	-0.005	0.003	-0.008
30	5	0.013	0.003	0.011
50	11	-0.005	0.003	-0.008
50	12	-0.005	0.003	-0.008
50	13	-0.005	0.003	-0.008
50	14	-0.005	0.003	-0.008
50	15	-0.005	0.003	-0.008
100	22	-0.010	-0.012	0.002
100	23	0.008	-0.012	0.020
100	24	-0.010	-0.012	0.002
100	25	-0.010	-0.012	0.002
100	26	-0.010	-0.012	0.002
100	27	-0.010	-0.012	0.002
100	28	-0.010	-0.012	0.002
100	29	0.008	-0.012	0.020
100	30	-0.010	-0.012	0.002
100	31	0.008	-0.012	0.020
100	32	-0.010	-0.012	0.002
100	33	0.008	-0.012	0.020
100	34	0.008	0.007	0.002
100	35	-0.010	-0.012	0.002
100	36	0.008	-0.012	0.020
100	37	-0.010	-0.031	0.020
100	38	-0.010	-0.012	0.002
100	39	0.008	-0.031	0.039
100	41	-0.010	-0.012	0.002
100	42	-0.010	-0.012	0.002
100	43	-0.010	0.007	-0.017
100	44	0.008	-0.012	0.020
	Max	0.013	0.007	0.054
	Average	-0.003	-0.012	0.009
	Min	-0.010	-0.046	-0.017
	Std Dev	0.008	0.015	0.018

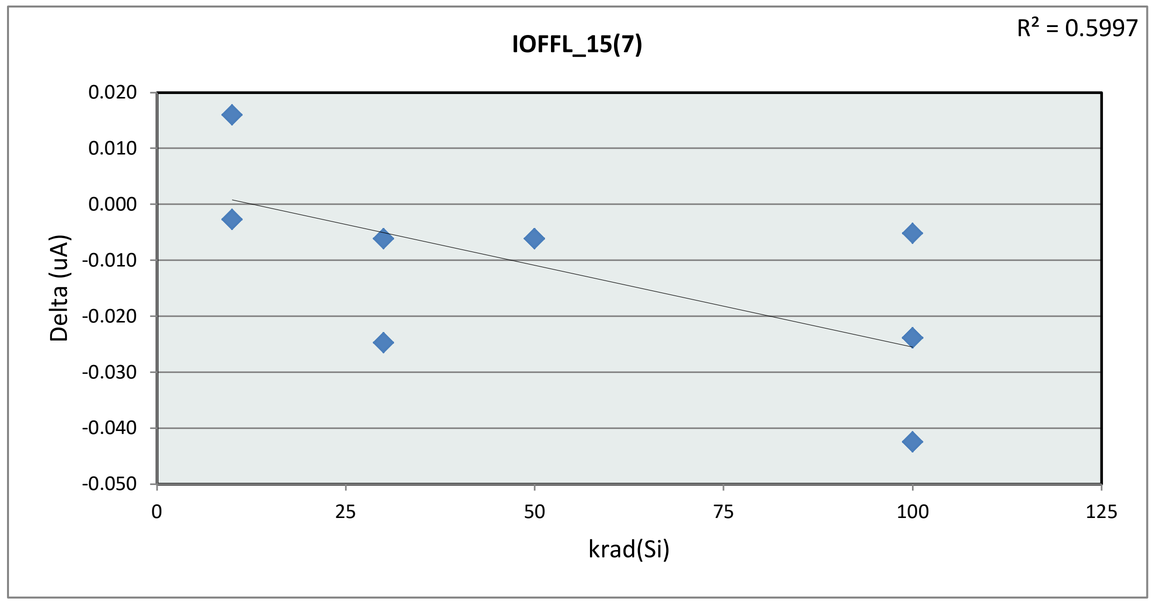


	IOFFL_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.046	0.003	0.003	-0.031
Average	-0.042	0.003	0.003	-0.012
Max	-0.027	0.003	0.003	0.007
UL	150.000	150.000	150.000	150.000

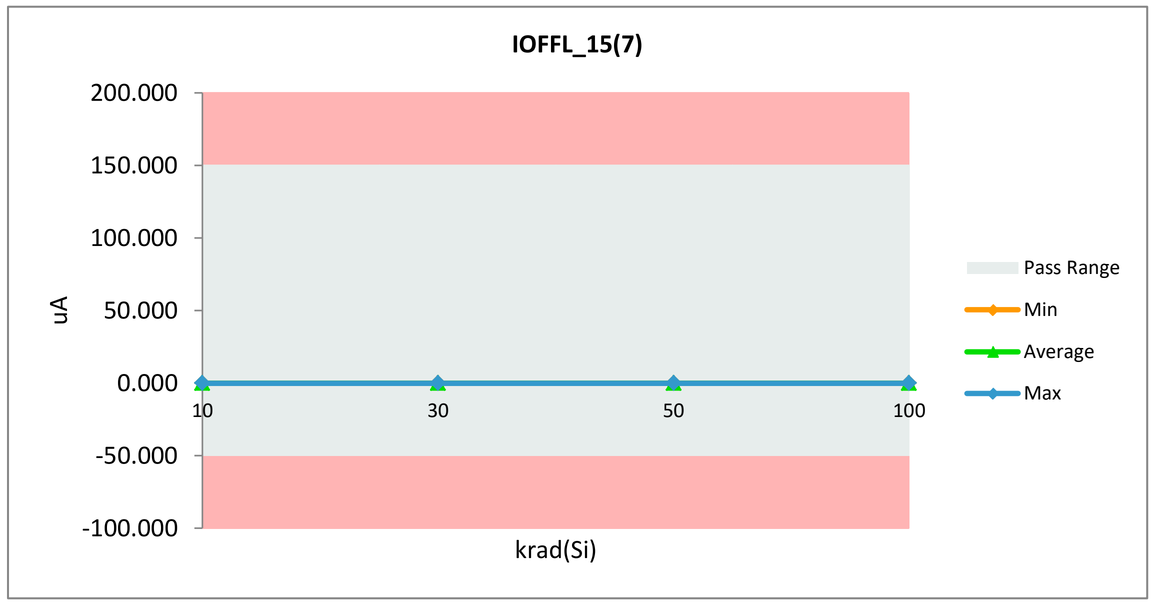


HDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_15(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.002	-0.018	0.016
10	2	0.017	0.001	0.016
10	3	-0.002	0.001	-0.003
10	4	-0.002	0.001	-0.003
10	5	-0.002	0.001	-0.003
30	1	-0.016	-0.010	-0.006
30	2	-0.016	0.009	-0.025
30	3	-0.016	0.009	-0.025
30	4	-0.016	-0.010	-0.006
30	5	-0.016	-0.010	-0.006
50	11	-0.016	-0.010	-0.006
50	12	-0.016	-0.010	-0.006
50	13	-0.016	-0.010	-0.006
50	14	-0.016	-0.010	-0.006
50	15	-0.016	-0.010	-0.006
100	22	-0.002	0.022	-0.024
100	23	-0.002	0.041	-0.042
100	24	-0.002	0.022	-0.024
100	25	-0.002	0.022	-0.024
100	26	-0.002	0.022	-0.024
100	27	-0.002	0.022	-0.024
100	28	-0.002	0.022	-0.024
100	29	-0.002	0.022	-0.024
100	30	-0.002	0.022	-0.024
100	31	-0.002	0.022	-0.024
100	32	-0.002	0.003	-0.005
100	33	-0.021	0.003	-0.024
100	34	-0.002	0.022	-0.024
100	35	-0.002	0.022	-0.024
100	36	-0.002	0.022	-0.024
100	37	-0.002	0.041	-0.042
100	38	-0.021	0.022	-0.042
100	39	-0.002	0.022	-0.024
100	41	-0.002	0.022	-0.024
100	42	-0.002	0.022	-0.024
100	43	-0.002	0.022	-0.024
100	44	-0.002	0.022	-0.024
	Max	0.017	0.041	0.016
	Average	-0.006	0.011	-0.017
	Min	-0.021	-0.018	-0.042
	Std Dev	0.008	0.016	0.014



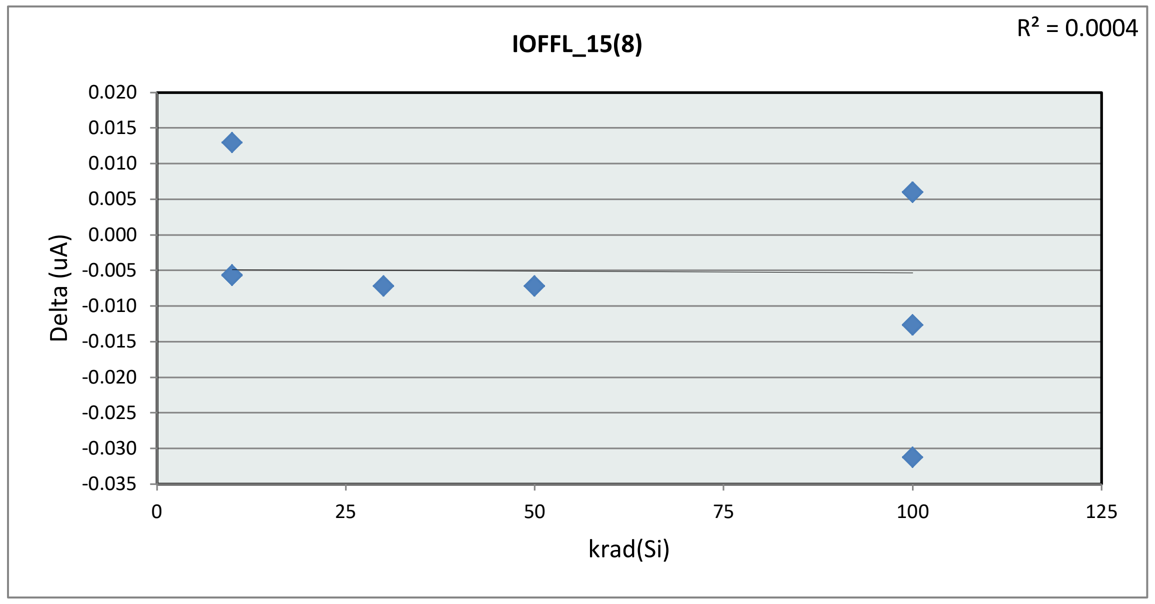
	IOFFL_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.018	-0.010	-0.010	0.003
Average	-0.003	-0.002	-0.010	0.022
Max	0.001	0.009	-0.010	0.041
UL	150.000	150.000	150.000	150.000



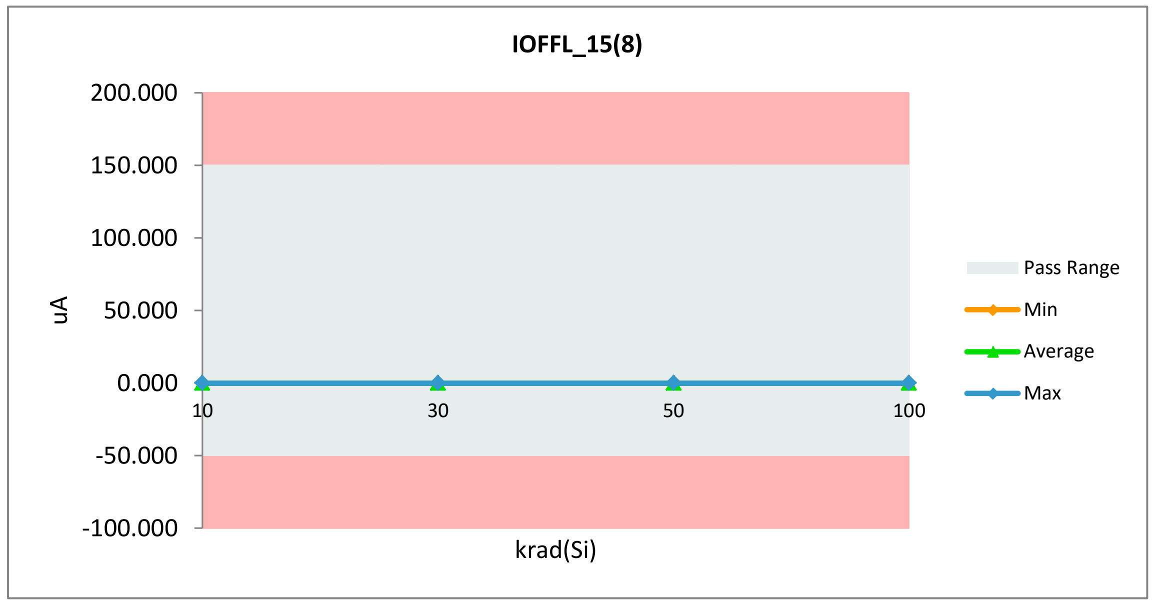
HDR Biased TID Report
SN55LVCP22A-SP

	IOFFL_15(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-0.007	-0.001	-0.006
10	2	-0.007	-0.020	0.013
10	3	-0.026	-0.020	-0.006
10	4	-0.007	-0.001	-0.006
10	5	-0.007	-0.001	-0.006
30	1	-0.019	-0.012	-0.007
30	2	-0.019	-0.012	-0.007
30	3	-0.019	-0.012	-0.007
30	4	-0.019	-0.012	-0.007
30	5	-0.019	-0.012	-0.007
50	11	-0.019	-0.012	-0.007
50	12	-0.019	-0.012	-0.007
50	13	-0.019	-0.012	-0.007
50	14	-0.019	-0.012	-0.007
50	15	-0.019	-0.012	-0.007
100	22	-0.026	0.005	-0.031
100	23	-0.007	-0.013	0.006
100	24	-0.007	0.005	-0.013
100	25	-0.007	0.005	-0.013
100	26	-0.007	0.005	-0.013
100	27	-0.007	-0.013	0.006
100	28	-0.007	-0.013	0.006
100	29	-0.007	-0.013	0.006
100	30	-0.007	-0.013	0.006
100	31	-0.007	-0.013	0.006
100	32	-0.007	-0.013	0.006
100	33	-0.007	0.005	-0.013
100	34	-0.007	-0.013	0.006
100	35	-0.007	0.005	-0.013
100	36	-0.007	0.005	-0.013
100	37	-0.007	-0.013	0.006
100	38	-0.007	0.005	-0.013
100	39	-0.007	-0.013	0.006
100	41	-0.007	-0.013	0.006
100	42	-0.007	0.005	-0.013
100	43	-0.026	0.005	-0.031
100	44	-0.007	0.005	-0.013
	Max	-0.007	0.005	0.013
	Average	-0.012	-0.007	-0.005
	Min	-0.026	-0.020	-0.031
	Std Dev	0.007	0.009	0.010

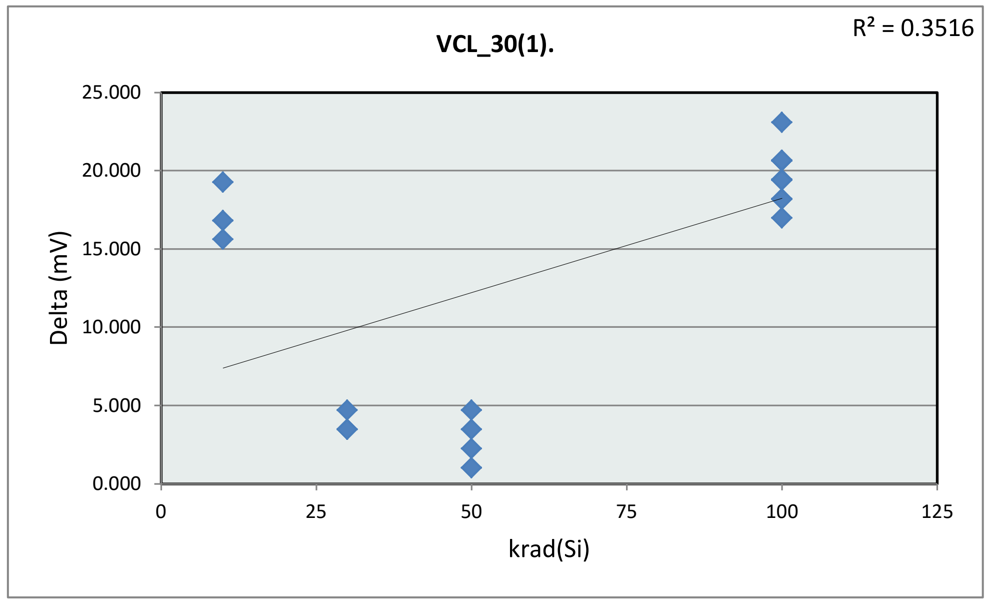


	IOFFL_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.020	-0.012	-0.012	-0.013
Average	-0.009	-0.012	-0.012	-0.004
Max	-0.001	-0.012	-0.012	0.005
UL	150.000	150.000	150.000	150.000

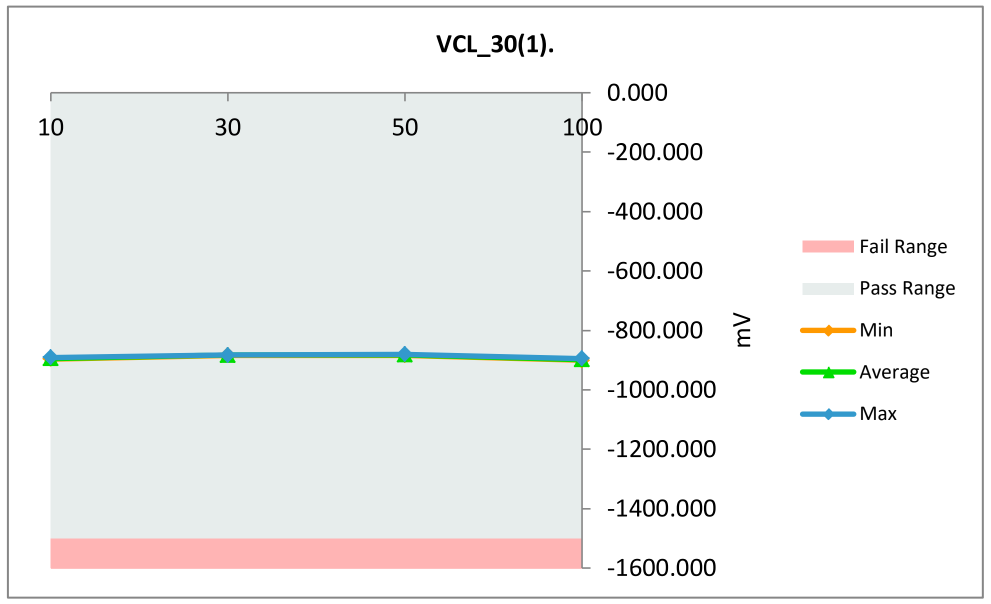


HDR Biased TID Report
SN55LVCP22A-SP

		VCL_30(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-877.695	-896.942	19.247
10	2	-877.695	-896.942	19.247
10	3	-878.923	-895.721	16.798
10	4	-875.239	-890.838	15.599
10	5	-876.467	-893.279	16.812
30	1	-879.195	-883.884	4.689
30	2	-879.195	-882.656	3.461
30	3	-879.195	-882.656	3.461
30	4	-880.424	-883.884	3.460
30	5	-880.424	-883.884	3.460
50	11	-880.424	-883.884	3.460
50	12	-879.195	-880.200	1.005
50	13	-879.195	-881.428	2.233
50	14	-877.967	-882.656	4.689
50	15	-880.424	-881.428	1.004
100	22	-880.151	-900.770	20.619
100	23	-877.695	-898.328	20.633
100	24	-878.923	-898.328	19.405
100	25	-880.151	-899.549	19.398
100	26	-877.695	-895.886	18.191
100	27	-877.695	-898.328	20.633
100	28	-877.695	-897.107	19.412
100	29	-876.467	-895.886	19.419
100	30	-877.695	-900.770	23.075
100	31	-878.923	-899.549	20.626
100	32	-878.923	-898.328	19.405
100	33	-875.239	-895.886	20.647
100	34	-880.151	-900.770	20.619
100	35	-880.151	-899.549	19.398
100	36	-880.151	-897.107	16.956
100	37	-880.151	-898.328	18.177
100	38	-874.011	-894.665	20.654
100	39	-878.923	-898.328	19.405
100	41	-880.151	-898.328	18.177
100	42	-880.151	-897.107	16.956
100	43	-878.923	-898.328	19.405
100	44	-880.151	-898.328	18.177
	Max	-874.011	-880.200	23.075
	Average	-878.698	-893.509	14.811
	Min	-880.424	-900.770	1.004
	Std Dev	1.632	6.997	7.389

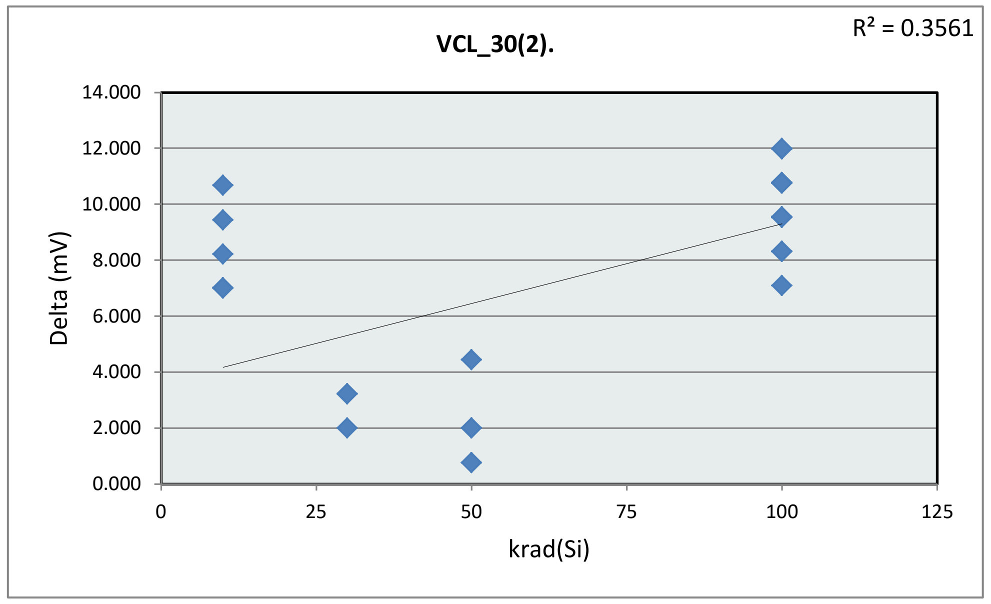


	VCL_30(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-896.942	-883.884	-883.884	-900.770
Average	-894.744	-883.393	-881.919	-898.162
Max	-890.838	-882.656	-880.200	-894.665
UL				

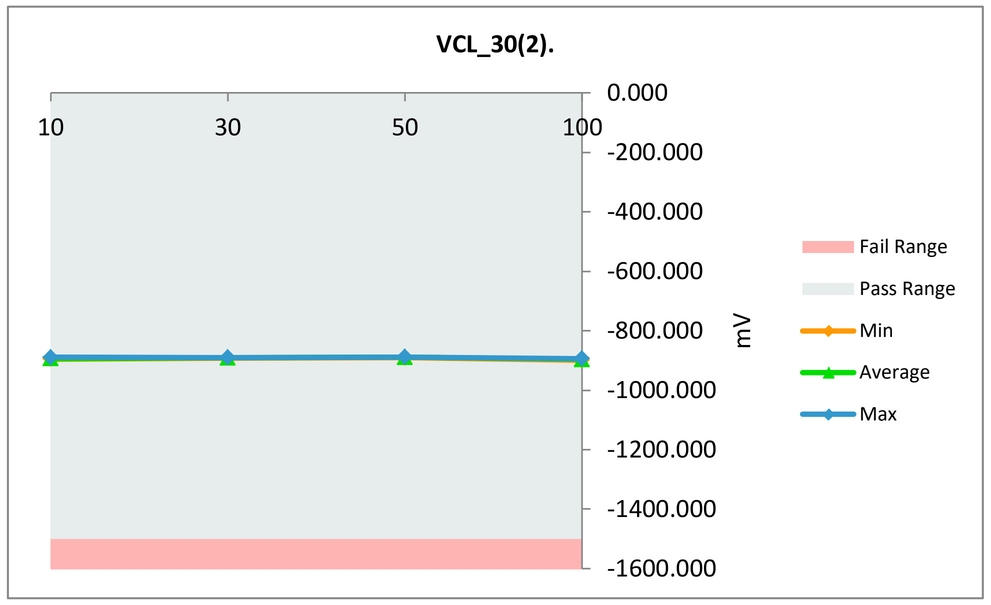


HDR Biased TID Report
SN55LVCP22A-SP

		VCL_30(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-885.048	-895.712	10.664
10	2	-886.275	-895.712	9.437
10	3	-886.275	-894.491	8.216
10	4	-882.594	-889.607	7.013
10	5	-885.048	-892.049	7.001
30	1	-889.031	-891.020	1.989
30	2	-886.577	-889.793	3.216
30	3	-887.804	-891.020	3.216
30	4	-887.804	-891.020	3.216
30	5	-889.031	-892.246	3.215
50	11	-889.031	-891.020	1.989
50	12	-887.804	-888.566	0.762
50	13	-887.804	-889.793	1.989
50	14	-885.350	-889.793	4.443
50	15	-887.804	-888.566	0.762
100	22	-887.501	-899.473	11.972
100	23	-885.048	-895.810	10.762
100	24	-887.501	-897.031	9.530
100	25	-887.501	-898.252	10.751
100	26	-886.275	-895.810	9.535
100	27	-886.275	-897.031	10.756
100	28	-885.048	-895.810	10.762
100	29	-885.048	-894.589	9.541
100	30	-885.048	-897.031	11.983
100	31	-887.501	-898.252	10.751
100	32	-887.501	-897.031	9.530
100	33	-883.821	-894.589	10.768
100	34	-888.728	-898.252	9.524
100	35	-888.728	-898.252	9.524
100	36	-887.501	-894.589	7.088
100	37	-888.728	-897.031	8.303
100	38	-882.594	-893.368	10.774
100	39	-886.275	-897.031	10.756
100	41	-887.501	-895.810	8.309
100	42	-887.501	-895.810	8.309
100	43	-886.275	-895.810	9.535
100	44	-887.501	-895.810	8.309
	Max	-882.594	-888.566	11.983
	Average	-886.721	-894.402	7.681
	Min	-889.031	-899.473	0.762
	Std Dev	1.682	3.144	3.476



	VCL_30(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-895.712	-892.246	-891.020	-899.473
Average	-893.514	-891.020	-889.548	-896.476
Max	-889.607	-889.793	-888.566	-893.368
UL				



HDR Biased TID Report
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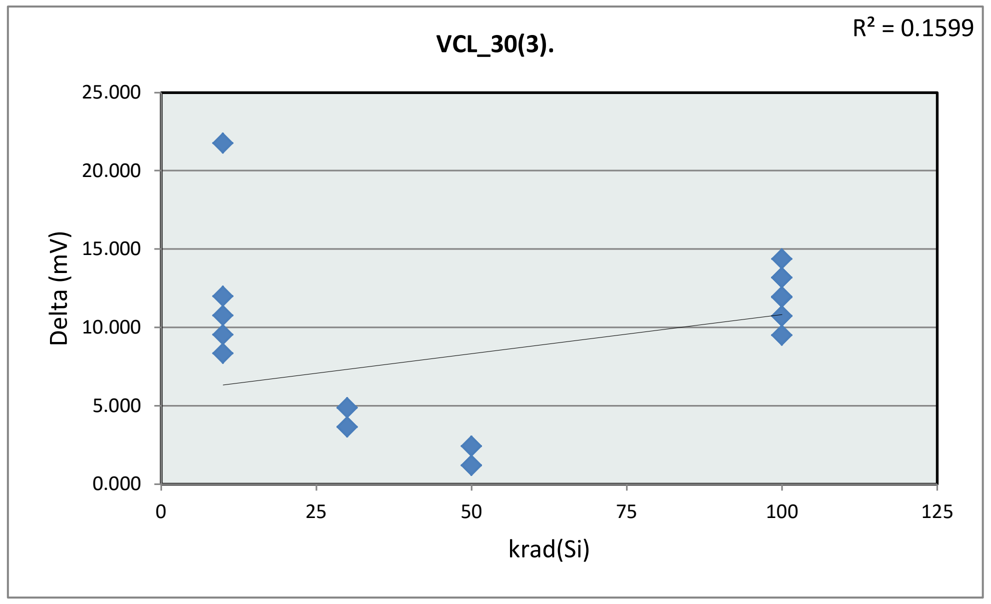
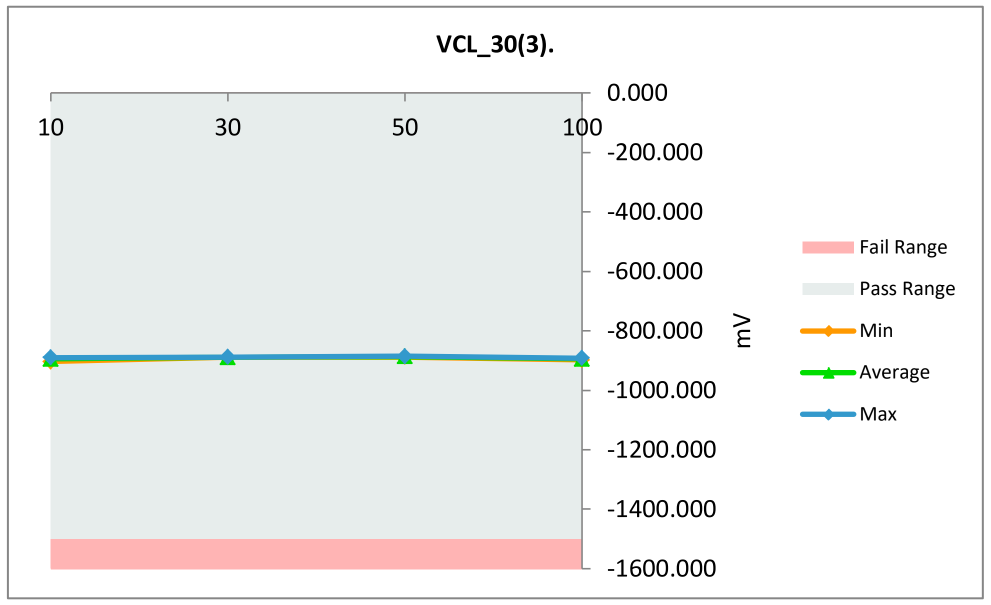
		VCL_30(3).	
	Test Site	SLL LAB	SLL LAB
	Tester	IMP	IMP
	Test Number	I2107203	I2107203
	Unit	mV	mV
	Max Limit		
	Min Limit	-1500	-1500

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-881.579	-903.336	21.757
10	2	-882.808	-893.571	10.763
10	3	-884.037	-893.571	9.534
10	4	-881.579	-889.909	8.330
10	5	-881.579	-893.571	11.992
30	1	-884.749	-888.397	3.648
30	2	-884.749	-888.397	3.648
30	3	-884.749	-888.397	3.648
30	4	-884.749	-889.626	4.877
30	5	-884.749	-889.626	4.877
50	11	-885.978	-888.397	2.419
50	12	-884.749	-885.937	1.188
50	13	-884.749	-885.937	1.188
50	14	-884.749	-887.167	2.418
50	15	-885.978	-887.167	1.189
100	22	-885.266	-897.190	11.924
100	23	-882.808	-895.970	13.162
100	24	-882.808	-894.749	11.941
100	25	-884.037	-898.411	14.374
100	26	-881.579	-893.528	11.949
100	27	-882.808	-894.749	11.941
100	28	-881.579	-893.528	11.949
100	29	-881.579	-892.308	10.729
100	30	-882.808	-895.970	13.162
100	31	-884.037	-897.190	13.153
100	32	-882.808	-895.970	13.162
100	33	-881.579	-893.528	11.949
100	34	-884.037	-897.190	13.153
100	35	-885.266	-895.970	10.704
100	36	-884.037	-893.528	9.491
100	37	-884.037	-894.749	10.712
100	38	-881.579	-892.308	10.729
100	39	-884.037	-894.749	10.712
100	41	-884.037	-894.749	10.712
100	42	-884.037	-894.749	10.712
100	43	-884.037	-894.749	10.712
100	44	-885.266	-894.749	9.483
	Max	-881.579	-885.937	21.757
	Average	-883.665	-893.070	9.405
	Min	-885.978	-903.336	1.188
	Std Dev	1.378	3.860	4.566



	VCL_30(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-903.336	-889.626	-888.397	-898.411
Average	-894.792	-888.889	-886.921	-895.026
Max	-889.909	-888.397	-885.937	-892.308
UL				



HDR Biased TID Report
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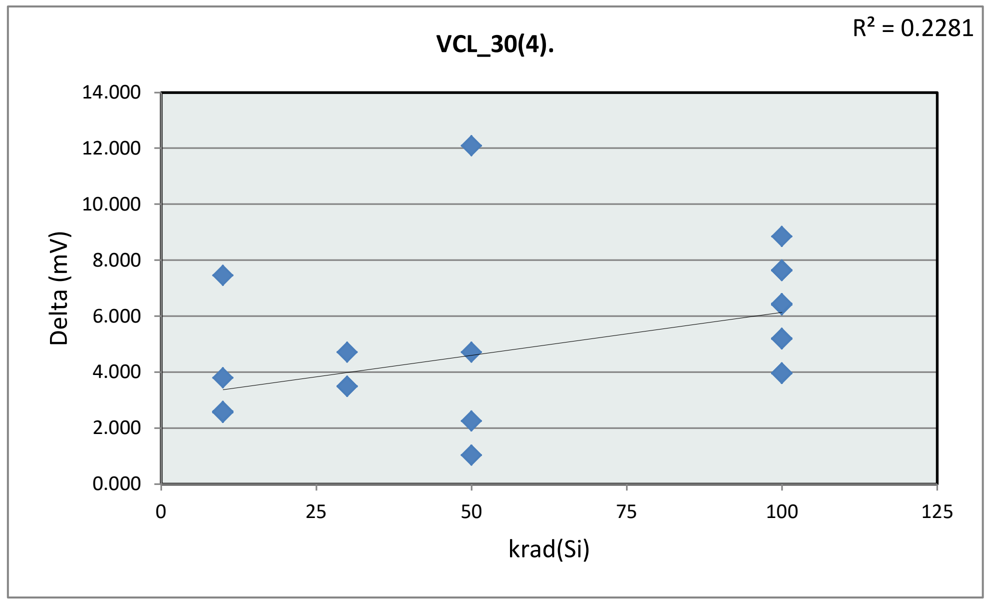
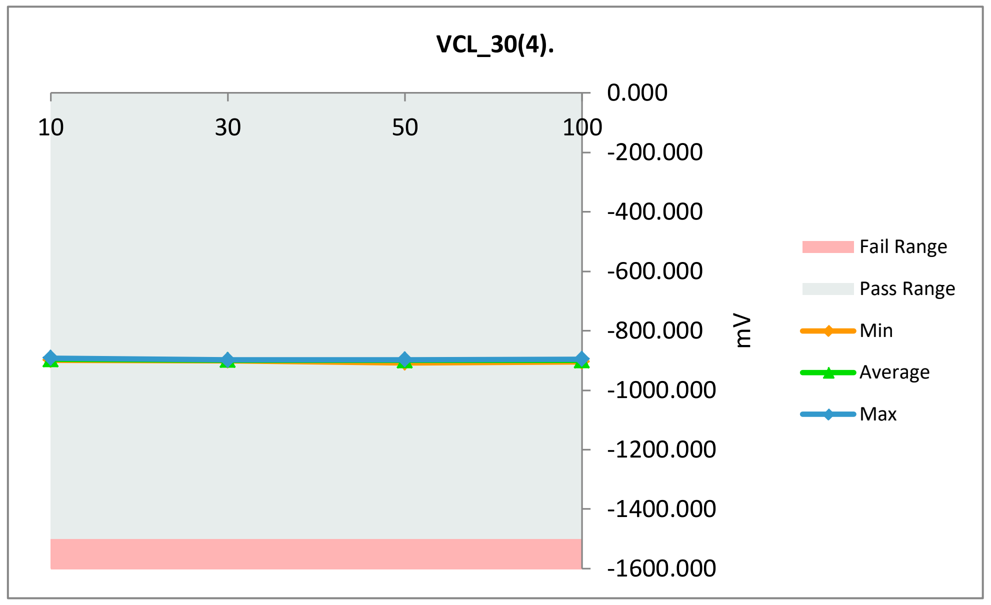
		VCL_30(4).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-1500	-1500	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-891.641	-899.100	7.459
10	2	-894.098	-897.880	3.782
10	3	-895.326	-897.880	2.554
10	4	-889.185	-891.781	2.596
10	5	-891.641	-894.220	2.579
30	1	-894.781	-898.263	3.482
30	2	-896.010	-899.491	3.481
30	3	-896.010	-899.491	3.481
30	4	-896.010	-900.719	4.709
30	5	-896.010	-899.491	3.481
50	11	-896.010	-908.090	12.080
50	12	-896.010	-897.034	1.024
50	13	-896.010	-897.034	1.024
50	14	-893.553	-898.263	4.710
50	15	-896.010	-898.263	2.253
100	22	-895.326	-904.161	8.835
100	23	-892.869	-899.281	6.412
100	24	-894.098	-900.501	6.403
100	25	-895.326	-901.721	6.395
100	26	-892.869	-898.062	5.193
100	27	-892.869	-900.501	7.632
100	28	-891.641	-899.281	7.640
100	29	-891.641	-898.062	6.421
100	30	-894.098	-901.721	7.623
100	31	-894.098	-901.721	7.623
100	32	-894.098	-900.501	6.403
100	33	-890.413	-898.062	7.649
100	34	-895.326	-902.941	7.615
100	35	-896.554	-900.501	3.947
100	36	-894.098	-898.062	3.964
100	37	-894.098	-900.501	6.403
100	38	-889.185	-895.622	6.437
100	39	-895.326	-900.501	5.175
100	41	-894.098	-899.281	5.183
100	42	-894.098	-899.281	5.183
100	43	-895.326	-899.281	3.955
100	44	-895.326	-899.281	3.955
	Max	-889.185	-891.781	12.080
	Average	-894.083	-899.347	5.263
	Min	-896.554	-908.090	1.024
	Std Dev	1.952	2.698	2.333

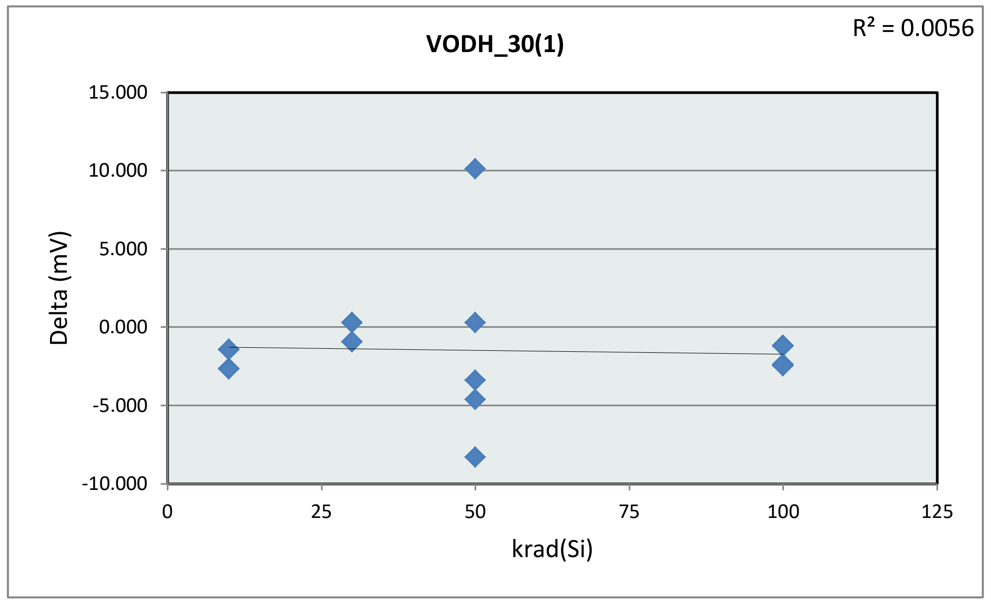


	VCL_30(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-899.100	-900.719	-908.090	-904.161
Average	-896.172	-899.491	-899.737	-899.947
Max	-891.781	-898.263	-897.034	-895.622
UL				

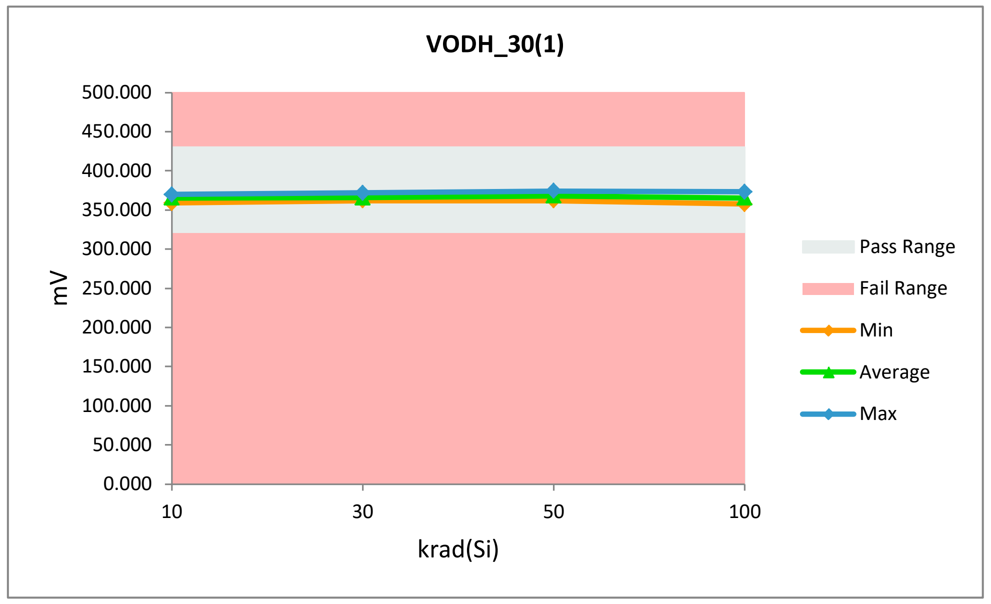


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	361.034	363.698	-2.664
10	2	364.715	366.138	-1.423
10	3	357.350	358.804	-1.454
10	4	367.168	369.797	-2.629
10	5	365.943	368.585	-2.642
30	1	365.917	366.849	-0.932
30	2	364.689	365.621	-0.932
30	3	372.056	371.761	0.295
30	4	362.235	361.941	0.294
30	5	361.006	361.938	-0.932
50	11	365.918	374.213	-8.295
50	12	362.238	365.623	-3.385
50	13	372.056	361.945	10.111
50	14	367.144	366.849	0.295
50	15	367.145	371.761	-4.616
100	22	361.033	362.239	-1.206
100	23	370.851	373.233	-2.382
100	24	367.168	368.339	-1.171
100	25	363.488	364.682	-1.194
100	26	367.169	369.568	-2.399
100	27	364.716	367.131	-2.415
100	28	365.941	368.340	-2.399
100	29	363.489	364.687	-1.198
100	30	361.032	363.453	-2.421
100	31	361.033	363.457	-2.424
100	32	364.714	367.123	-2.409
100	33	365.942	368.345	-2.403
100	34	363.487	364.681	-1.194
100	35	361.034	362.241	-1.207
100	36	368.397	369.568	-1.171
100	37	362.260	363.454	-1.194
100	38	367.167	369.556	-2.389
100	39	357.350	358.567	-1.217
100	41	358.579	359.799	-1.220
100	42	359.807	362.247	-2.440
100	43	354.898	357.354	-2.456
100	44	365.942	367.123	-1.181
	Max	372.056	374.213	10.111
	Average	364.111	365.695	-1.584
	Min	354.898	357.354	-8.295
	Std Dev	3.948	4.102	2.465

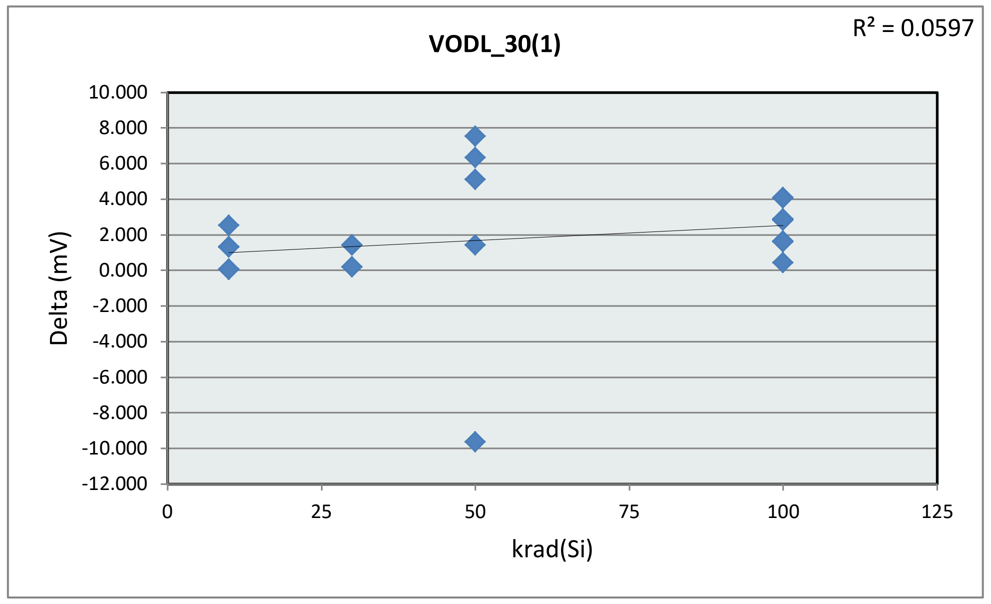


	VODH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	358.804	361.938	361.945	357.354
Average	365.404	365.622	368.078	365.236
Max	369.797	371.761	374.213	373.233
UL	430.000	430.000	430.000	430.000

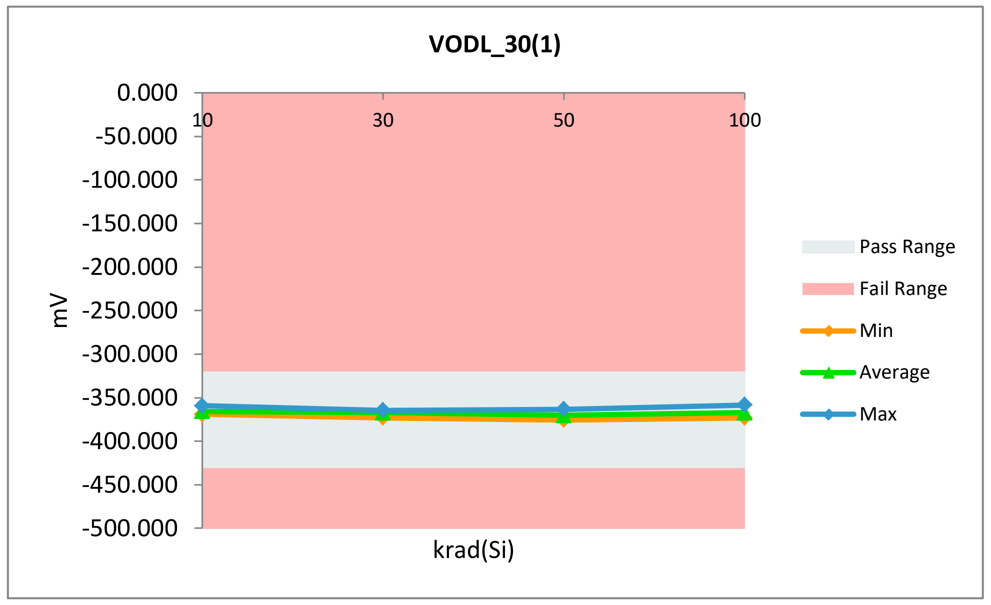


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-363.028	-365.545	2.517
10	2	-366.710	-366.770	0.060
10	3	-358.121	-359.447	1.326
10	4	-366.711	-367.997	1.286
10	5	-369.164	-369.209	0.045
30	1	-365.566	-365.747	0.181
30	2	-366.794	-368.203	1.409
30	3	-371.700	-373.107	1.407
30	4	-363.111	-364.520	1.409
30	5	-364.340	-364.523	0.183
50	11	-368.020	-375.563	7.543
50	12	-363.108	-369.428	6.320
50	13	-372.927	-363.289	-9.638
50	14	-368.021	-369.429	1.408
50	15	-369.247	-374.334	5.087
100	22	-363.028	-364.650	1.622
100	23	-370.392	-373.203	2.811
100	24	-366.711	-369.545	2.834
100	25	-366.710	-369.537	2.827
100	26	-369.164	-371.980	2.816
100	27	-369.164	-371.974	2.810
100	28	-370.393	-373.209	2.816
100	29	-363.028	-364.645	1.617
100	30	-361.802	-365.879	4.077
100	31	-361.802	-365.875	4.073
100	32	-365.484	-369.540	4.056
100	33	-366.710	-369.539	2.829
100	34	-366.710	-369.537	2.827
100	35	-360.573	-363.426	2.853
100	36	-369.165	-371.981	2.816
100	37	-364.257	-365.879	1.622
100	38	-367.939	-369.550	1.611
100	39	-359.348	-359.770	0.422
100	41	-360.574	-362.202	1.628
100	42	-360.573	-362.199	1.626
100	43	-355.665	-358.540	2.875
100	44	-365.483	-367.096	1.613
	Max	-355.665	-358.540	7.543
	Average	-365.439	-367.483	2.044
	Min	-372.927	-375.563	-9.638
	Std Dev	3.944	4.247	2.555



	VODL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-369.209	-373.107	-375.563	-373.209
Average	-365.794	-367.220	-370.409	-367.262
Max	-359.447	-364.520	-363.289	-358.540
UL	-320.000	-320.000	-320.000	-320.000



HDR Biased TID Report
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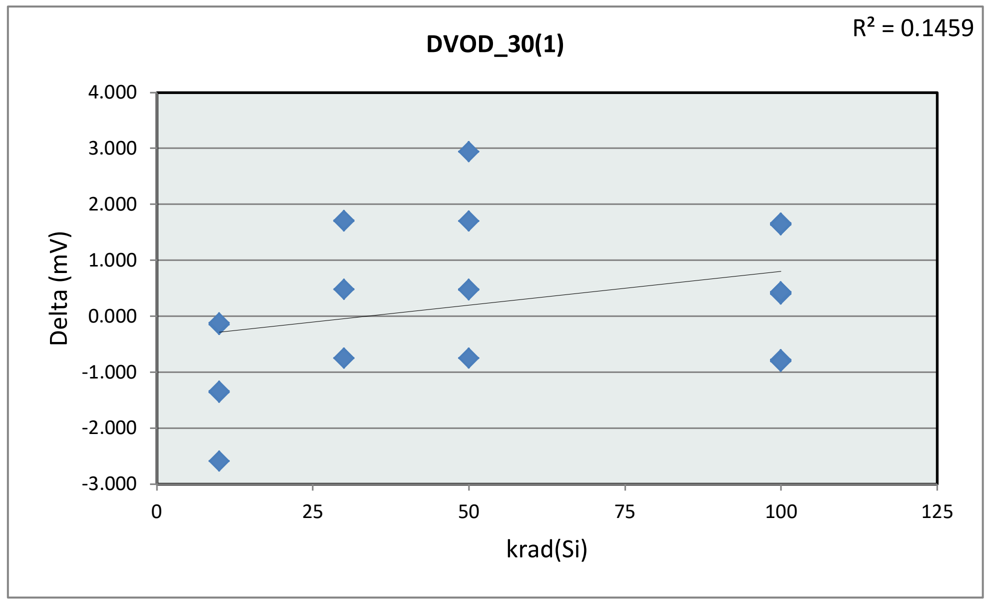
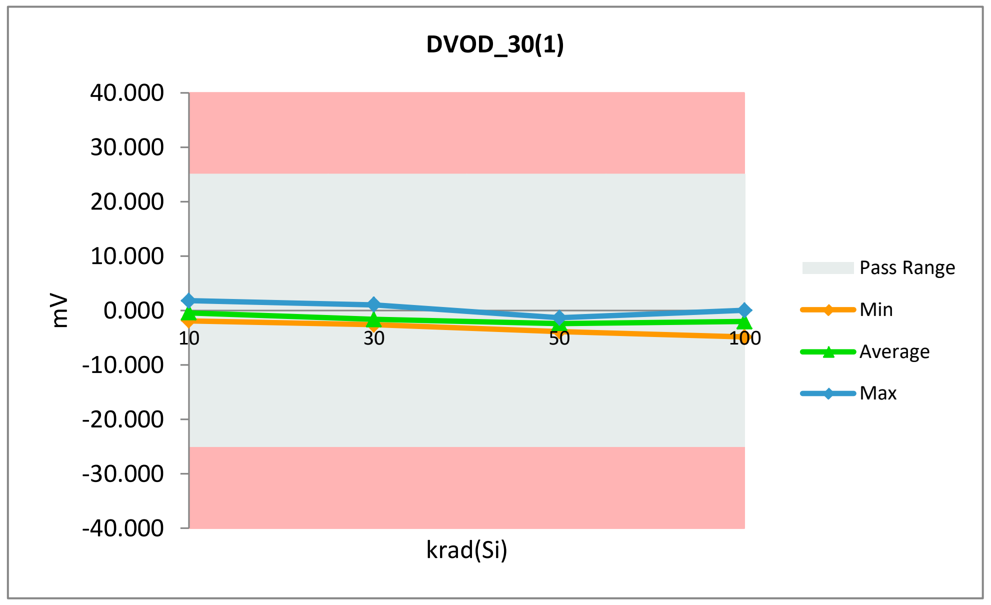
		DVOD_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-1.994	-1.847	-0.147
10	2	-1.996	-0.633	-1.363
10	3	-0.770	-0.643	-0.127
10	4	0.457	1.800	-1.343
10	5	-3.221	-0.624	-2.597
30	1	0.351	1.102	-0.751
30	2	-2.105	-2.582	0.477
30	3	0.356	-1.346	1.702
30	4	-0.875	-2.579	1.704
30	5	-3.334	-2.584	-0.750
50	11	-2.102	-1.350	-0.752
50	12	-0.870	-3.806	2.936
50	13	-0.871	-1.345	0.474
50	14	-0.878	-2.579	1.701
50	15	-2.102	-2.573	0.471
100	22	-1.995	-2.411	0.416
100	23	0.459	0.030	0.428
100	24	0.457	-1.206	1.663
100	25	-3.223	-4.856	1.633
100	26	-1.995	-2.411	0.416
100	27	-4.448	-4.843	0.395
100	28	-4.452	-4.869	0.417
100	29	0.461	0.043	0.418
100	30	-0.770	-2.426	1.656
100	31	-0.769	-2.418	1.649
100	32	-0.769	-2.417	1.648
100	33	-0.768	-1.194	0.426
100	34	-3.223	-4.856	1.633
100	35	0.460	-1.185	1.645
100	36	-0.768	-2.413	1.645
100	37	-1.997	-2.425	0.428
100	38	-0.772	0.006	-0.778
100	39	-1.998	-1.203	-0.795
100	41	-1.994	-2.403	0.409
100	42	-0.766	0.048	-0.813
100	43	-0.767	-1.186	0.419
100	44	0.459	0.028	0.431
	Max	0.461	1.800	2.936
	Average	-1.328	-1.788	0.460
	Min	-4.452	-4.869	-2.597
	Std Dev	1.371	1.600	1.152

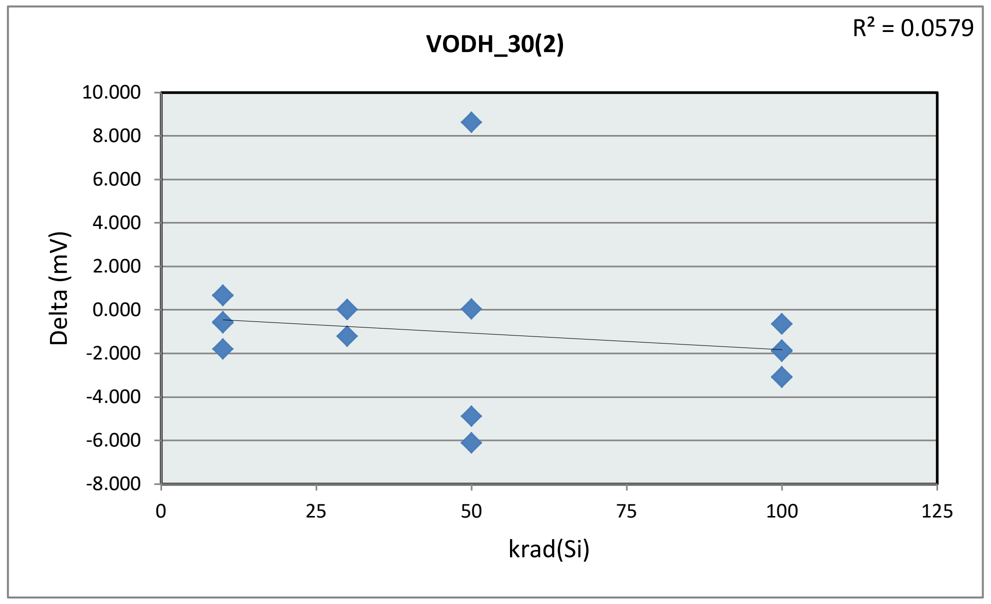


	DVOD_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-1.847	-2.584	-3.806	-4.869
Average	-0.389	-1.598	-2.331	-2.026
Max	1.800	1.102	-1.345	0.048
UL	25.000	25.000	25.000	25.000

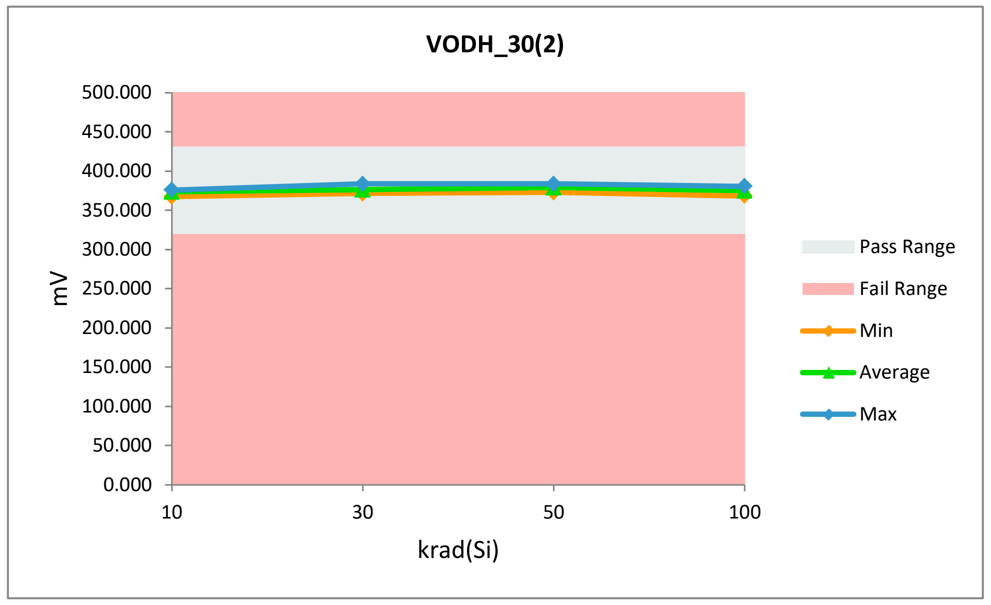


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	371.419	373.222	-1.803
10	2	375.099	374.440	0.659
10	3	366.506	367.101	-0.595
10	4	375.097	375.652	-0.555
10	5	376.330	375.669	0.661
30	1	375.145	375.129	0.016
30	2	376.378	376.356	0.022
30	3	382.513	383.720	-1.207
30	4	371.465	371.447	0.018
30	5	372.690	373.901	-1.211
50	11	377.605	383.720	-6.115
50	12	372.692	377.584	-4.892
50	13	381.290	372.674	8.616
50	14	378.836	378.811	0.025
50	15	375.156	381.266	-6.110
100	22	370.188	372.086	-1.898
100	23	380.010	380.652	-0.642
100	24	372.644	375.754	-3.110
100	25	373.867	375.740	-1.873
100	26	378.781	379.423	-0.642
100	27	375.096	376.967	-1.871
100	28	377.552	379.416	-1.864
100	29	371.413	373.302	-1.889
100	30	368.962	370.870	-1.908
100	31	372.639	375.744	-3.105
100	32	375.097	376.971	-1.874
100	33	372.645	374.534	-1.889
100	34	375.101	376.982	-1.881
100	35	372.634	375.723	-3.089
100	36	376.330	376.990	-0.660
100	37	371.418	373.315	-1.897
100	38	373.872	375.759	-1.887
100	39	368.952	369.613	-0.661
100	41	366.499	368.396	-1.897
100	42	372.641	373.302	-0.661
100	43	366.506	368.416	-1.910
100	44	373.871	375.752	-1.881
	Max	382.513	383.720	8.616
	Average	373.917	375.308	-1.391
	Min	366.499	367.101	-6.115
	Std Dev	3.843	3.863	2.297

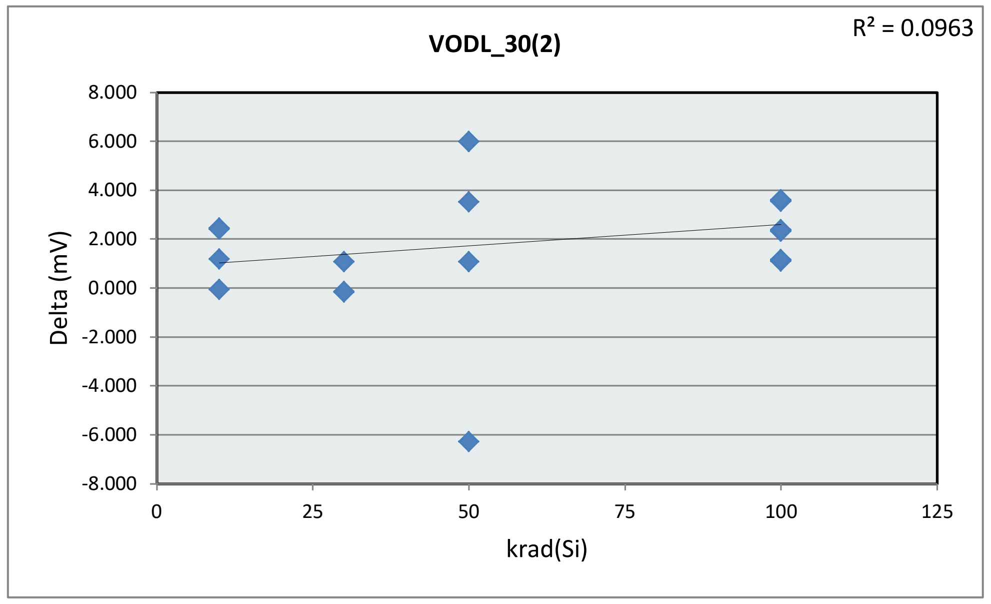


	VODH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	367.101	371.447	372.674	368.396
Average	373.217	376.111	378.811	374.805
Max	375.669	383.720	383.720	380.652
UL	430.000	430.000	430.000	430.000

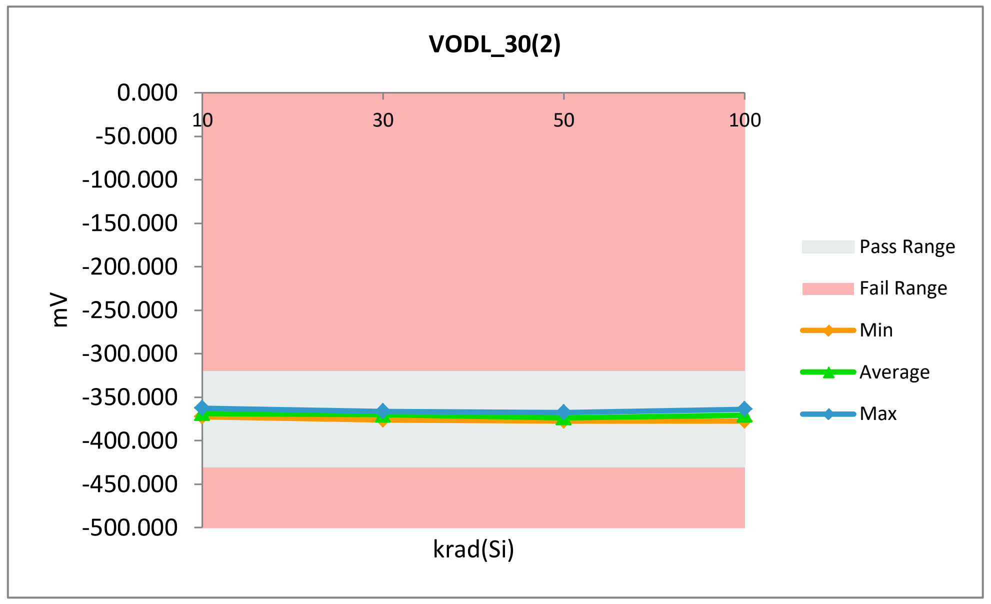


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-363.771	-366.192	2.421
10	2	-369.909	-371.085	1.176
10	3	-360.091	-362.536	2.445
10	4	-369.912	-372.319	2.407
10	5	-371.133	-371.072	-0.061
30	1	-368.809	-368.648	-0.161
30	2	-372.486	-372.329	-0.157
30	3	-374.945	-376.012	1.067
30	4	-366.351	-366.193	-0.158
30	5	-366.354	-367.420	1.066
50	11	-373.714	-377.239	3.525
50	12	-367.579	-373.557	5.978
50	13	-373.712	-367.420	-6.292
50	14	-374.938	-376.011	1.073
50	15	-367.571	-373.557	5.986
100	22	-363.774	-367.359	3.585
100	23	-373.590	-377.128	3.538
100	24	-368.682	-371.025	2.343
100	25	-368.687	-369.817	1.130
100	26	-372.364	-374.689	2.325
100	27	-369.912	-372.256	2.344
100	28	-373.593	-375.919	2.326
100	29	-366.231	-369.813	3.582
100	30	-361.317	-364.909	3.592
100	31	-366.233	-369.813	3.580
100	32	-371.139	-374.698	3.559
100	33	-371.135	-373.465	2.330
100	34	-367.453	-371.019	3.566
100	35	-367.465	-371.057	3.592
100	36	-371.134	-372.235	1.101
100	37	-367.453	-369.798	2.345
100	38	-371.136	-372.242	1.106
100	39	-363.782	-364.943	1.161
100	41	-361.326	-363.718	2.392
100	42	-367.458	-369.811	2.353
100	43	-360.092	-363.697	3.605
100	44	-366.228	-368.584	2.356
	Max	-360.091	-362.536	5.986
	Average	-368.418	-370.529	2.112
	Min	-374.945	-377.239	-6.292
	Std Dev	4.092	3.918	2.048

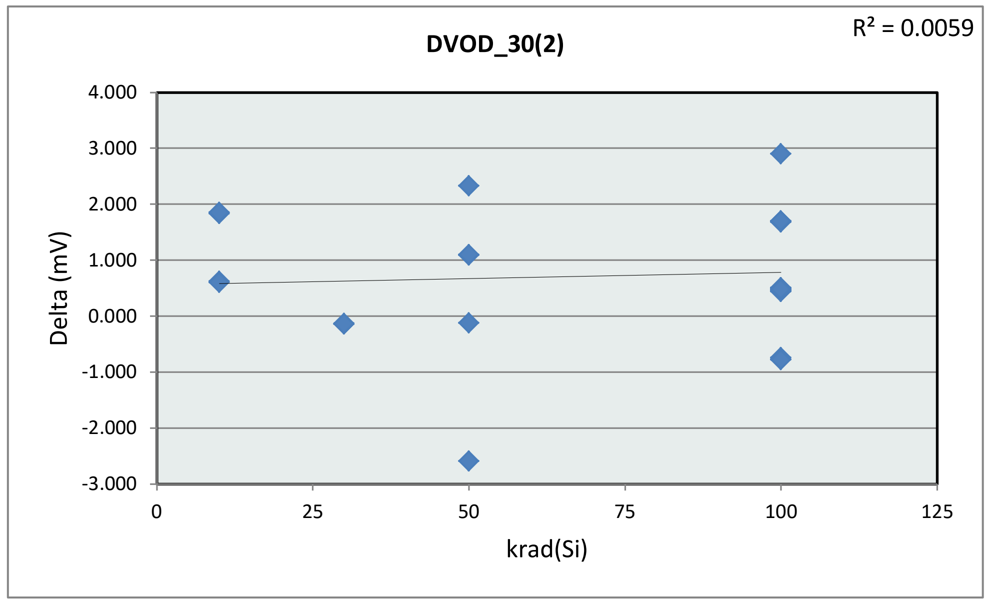


	VODL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-372.319	-376.012	-377.239	-377.128
Average	-368.641	-370.120	-373.557	-370.363
Max	-362.536	-366.193	-367.420	-363.697
UL	-320.000	-320.000	-320.000	-320.000

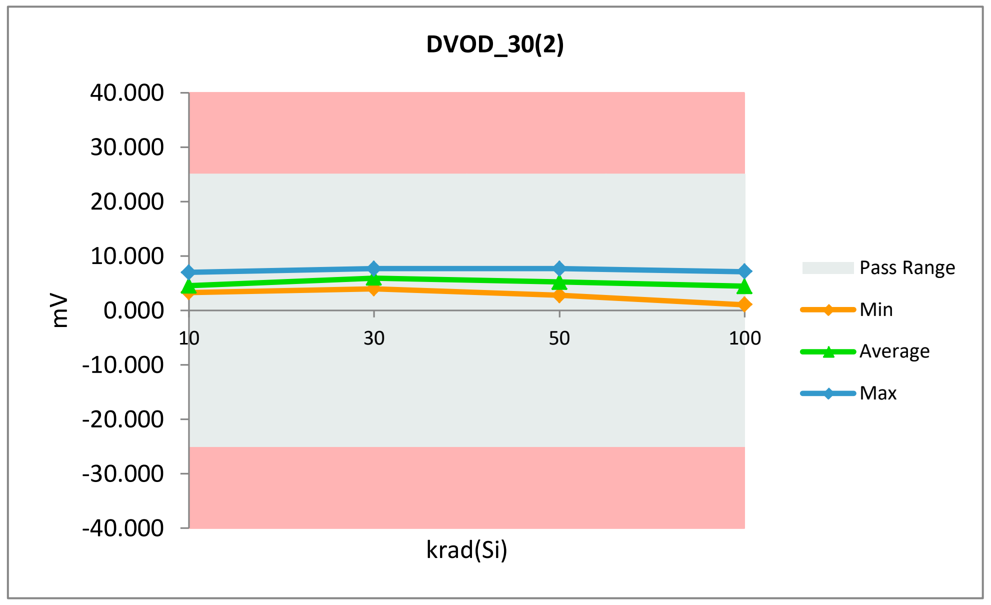


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	7.648	7.030	0.618
10	2	5.190	3.355	1.835
10	3	6.415	4.565	1.850
10	4	5.185	3.333	1.852
10	5	5.197	4.597	0.600
30	1	6.336	6.481	-0.145
30	2	3.892	4.027	-0.135
30	3	7.569	7.709	-0.140
30	4	5.114	5.254	-0.140
30	5	6.336	6.481	-0.145
50	11	3.891	6.481	-2.590
50	12	5.113	4.027	1.086
50	13	7.578	5.254	2.324
50	14	3.898	2.800	1.098
50	15	7.585	7.709	-0.124
100	22	6.414	4.727	1.687
100	23	6.421	3.524	2.897
100	24	3.961	4.729	-0.768
100	25	5.180	5.924	-0.744
100	26	6.417	4.735	1.682
100	27	5.184	4.712	0.472
100	28	3.959	3.496	0.463
100	29	5.182	3.488	1.694
100	30	7.645	5.961	1.684
100	31	6.406	5.931	0.475
100	32	3.958	2.273	1.685
100	33	1.510	1.069	0.441
100	34	7.648	5.963	1.685
100	35	5.169	4.666	0.503
100	36	5.196	4.755	0.441
100	37	3.965	3.517	0.448
100	38	2.736	3.517	-0.781
100	39	5.170	4.670	0.500
100	41	5.173	4.678	0.495
100	42	5.184	3.490	1.694
100	43	6.414	4.719	1.695
100	44	7.642	7.167	0.475
	Max	7.648	7.709	2.897
	Average	5.499	4.779	0.721
	Min	1.510	1.069	-2.590
	Std Dev	1.490	1.505	1.074

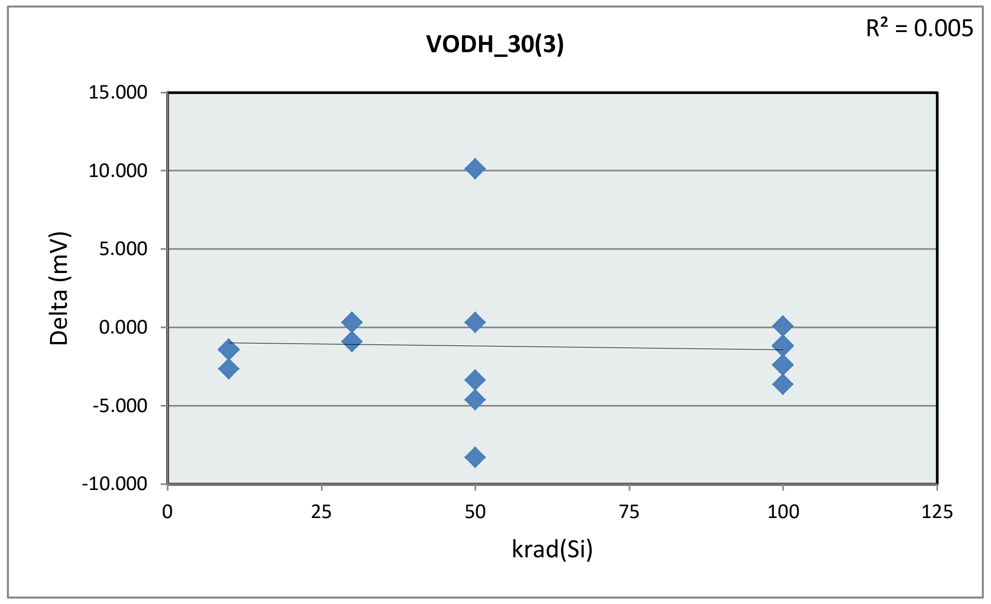


	DVOD_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.333	4.027	2.800	1.069
Average	4.576	5.990	5.254	4.441
Max	7.030	7.709	7.709	7.167
UL	25.000	25.000	25.000	25.000

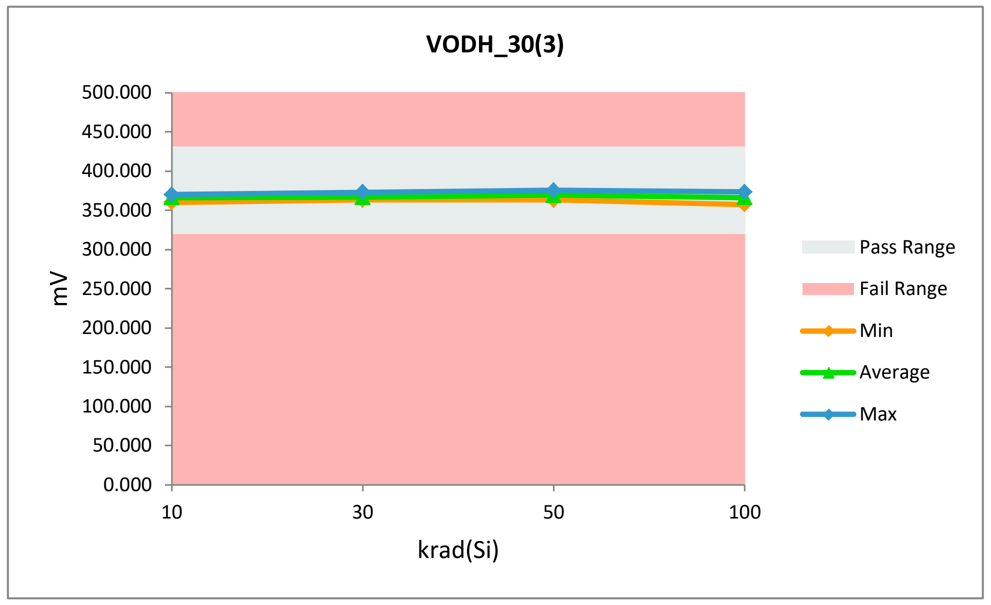


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	362.260	364.916	-2.656
10	2	365.941	367.355	-1.414
10	3	358.577	360.022	-1.445
10	4	368.395	369.793	-1.398
10	5	367.169	368.582	-1.413
30	1	367.142	366.847	0.295
30	2	365.914	366.845	-0.931
30	3	372.054	372.985	-0.931
30	4	363.461	363.166	0.295
30	5	363.459	363.163	0.296
50	11	367.143	375.438	-8.295
50	12	363.464	366.847	-3.383
50	13	373.281	363.170	10.111
50	14	368.369	368.074	0.295
50	15	368.370	372.985	-4.615
100	22	362.260	364.677	-2.417
100	23	372.077	373.226	-1.149
100	24	368.395	368.333	0.062
100	25	364.714	365.897	-1.183
100	26	369.623	369.563	0.060
100	27	365.942	367.125	-1.183
100	28	368.395	369.555	-1.160
100	29	363.488	364.683	-1.195
100	30	362.259	364.669	-2.410
100	31	361.032	364.673	-3.641
100	32	367.168	369.560	-2.392
100	33	367.168	368.339	-1.171
100	34	363.487	365.896	-2.409
100	35	361.033	363.457	-2.424
100	36	369.623	370.784	-1.161
100	37	364.713	365.891	-1.178
100	38	368.394	369.550	-1.156
100	39	358.577	359.784	-1.207
100	41	358.578	359.794	-1.216
100	42	361.034	362.242	-1.208
100	43	356.124	357.349	-1.225
100	44	367.168	368.340	-1.172
	Max	373.281	375.438	10.111
	Average	365.304	366.583	-1.279
	Min	356.124	357.349	-8.295
	Std Dev	4.053	4.039	2.485

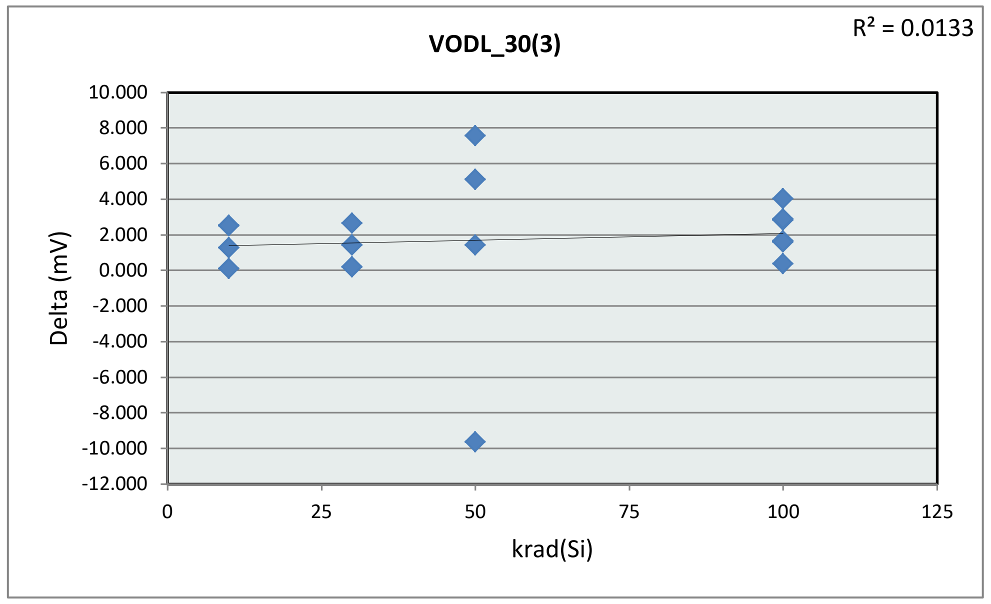


	VODH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	360.022	363.163	363.170	357.349
Average	366.134	366.601	369.303	366.063
Max	369.793	372.985	375.438	373.226
UL	430.000	430.000	430.000	430.000

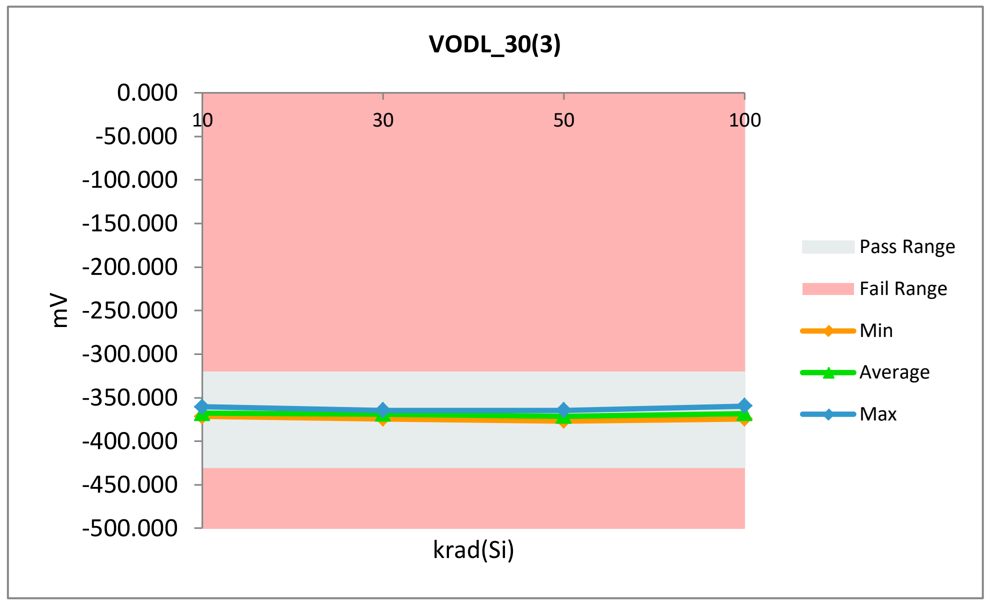


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-364.256	-366.770	2.514
10	2	-367.938	-369.217	1.279
10	3	-360.576	-360.672	0.096
10	4	-367.939	-370.444	2.505
10	5	-370.392	-371.655	1.263
30	1	-366.795	-368.204	1.409
30	2	-368.023	-369.433	1.410
30	3	-374.157	-374.337	0.180
30	4	-364.340	-364.522	0.182
30	5	-364.342	-366.979	2.637
50	11	-369.249	-376.793	7.544
50	12	-364.337	-369.431	5.094
50	13	-374.157	-364.519	-9.638
50	14	-369.251	-370.658	1.407
50	15	-370.476	-375.564	5.088
100	22	-364.256	-365.877	1.621
100	23	-370.393	-374.431	4.038
100	24	-369.166	-371.994	2.828
100	25	-369.165	-369.543	0.378
100	26	-370.393	-373.207	2.814
100	27	-369.165	-371.980	2.815
100	28	-371.621	-373.214	1.593
100	29	-364.256	-365.871	1.615
100	30	-364.258	-365.885	1.627
100	31	-364.257	-365.880	1.623
100	32	-366.711	-369.546	2.835
100	33	-367.938	-369.545	1.607
100	34	-369.166	-370.765	1.599
100	35	-361.802	-364.653	2.851
100	36	-370.393	-371.986	1.593
100	37	-365.484	-367.106	1.622
100	38	-369.167	-370.778	1.611
100	39	-359.349	-360.997	1.648
100	41	-360.574	-363.429	2.855
100	42	-361.801	-363.426	1.625
100	43	-356.893	-359.767	2.874
100	44	-367.938	-369.544	1.606
	Max	-356.893	-359.767	7.544
	Average	-366.767	-368.611	1.845
	Min	-374.157	-376.793	-9.638
	Std Dev	4.002	4.184	2.423



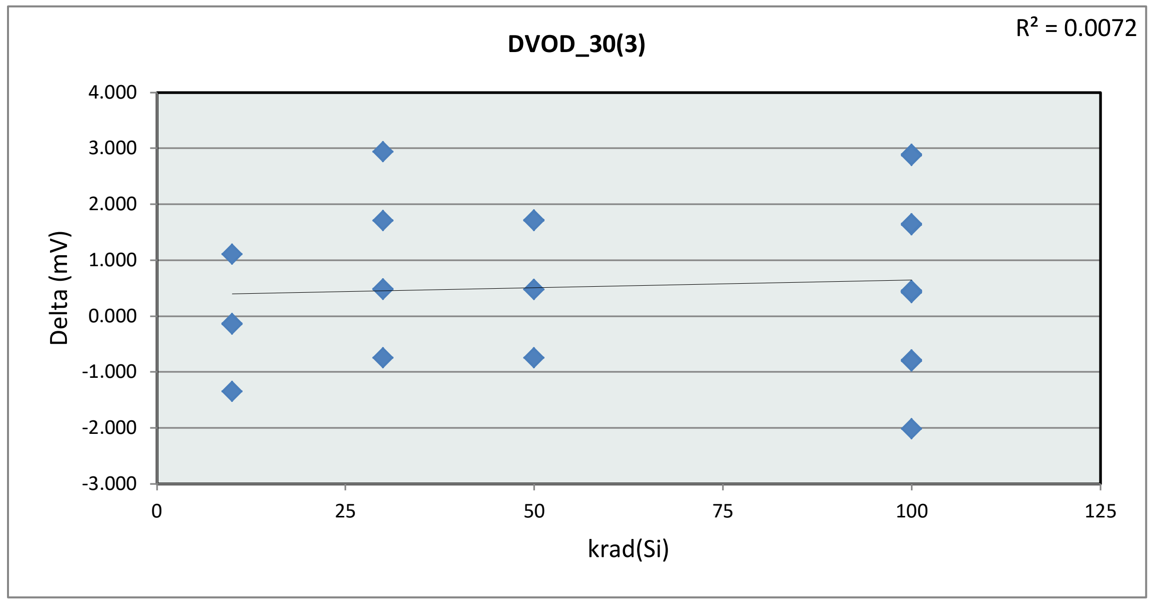
	VODL_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-371.655	-374.337	-376.793	-374.431
Average	-367.752	-368.695	-371.393	-368.156
Max	-360.672	-364.522	-364.519	-359.767
UL	-320.000	-320.000	-320.000	-320.000



HDR Biased TID Report
SN55LVCP22A-SP

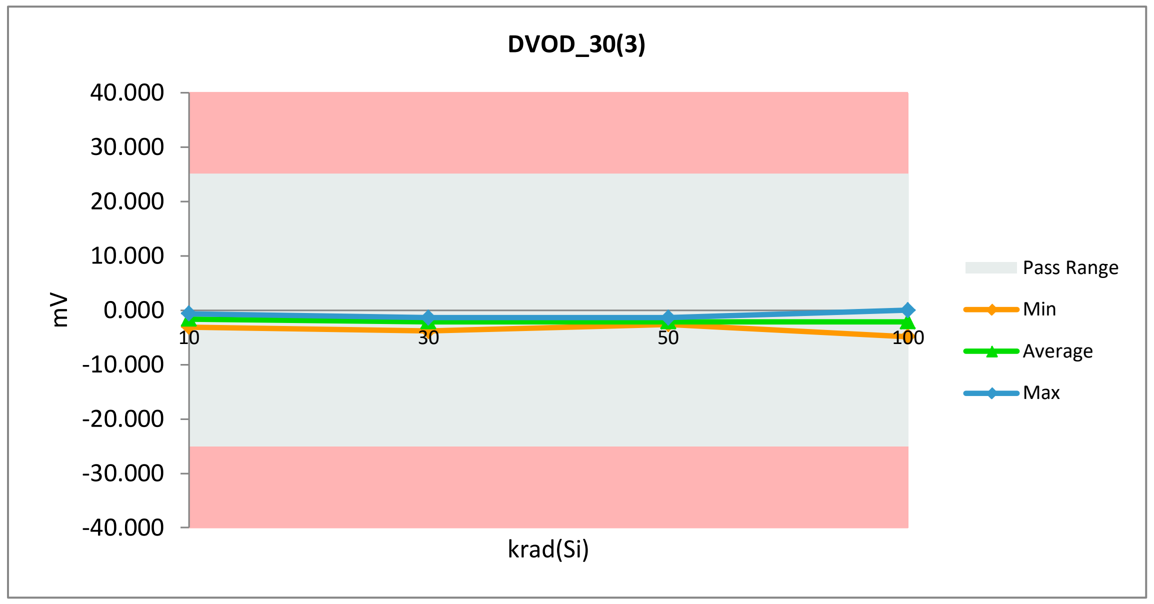
	DVOD_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-1.995	-1.854	-0.141
10	2	-1.997	-1.863	-0.134
10	3	-1.999	-0.650	-1.349
10	4	0.455	-0.651	1.106
10	5	-3.222	-3.074	-0.148
30	1	0.347	-1.357	1.704
30	2	-2.109	-2.587	0.478
30	3	-2.103	-1.352	-0.751
30	4	-0.879	-1.356	0.477
30	5	-0.884	-3.816	2.932
50	11	-2.106	-1.355	-0.751
50	12	-0.873	-2.583	1.710
50	13	-0.875	-1.349	0.474
50	14	-0.881	-2.585	1.704
50	15	-2.106	-2.579	0.473
100	22	-1.997	-1.200	-0.797
100	23	1.685	-1.204	2.889
100	24	-0.772	-3.661	2.889
100	25	-4.452	-3.646	-0.806
100	26	-0.770	-3.643	2.873
100	27	-3.223	-4.855	1.632
100	28	-3.226	-3.659	0.433
100	29	-0.768	-1.189	0.421
100	30	-1.999	-1.216	-0.783
100	31	-3.225	-1.207	-2.018
100	32	0.457	0.015	0.442
100	33	-0.770	-1.206	0.436
100	34	-5.679	-4.869	-0.810
100	35	-0.769	-1.196	0.427
100	36	-0.770	-1.203	0.433
100	37	-0.771	-1.214	0.443
100	38	-0.773	-1.227	0.454
100	39	-0.772	-1.213	0.441
100	41	-1.996	-3.635	1.639
100	42	-0.767	-1.184	0.417
100	43	-0.769	-2.418	1.649
100	44	-0.770	-1.204	0.434
	Max	1.685	0.015	2.932
	Average	-1.463	-2.028	0.565
	Min	-5.679	-4.869	-2.018
	Std Dev	1.399	1.225	1.206



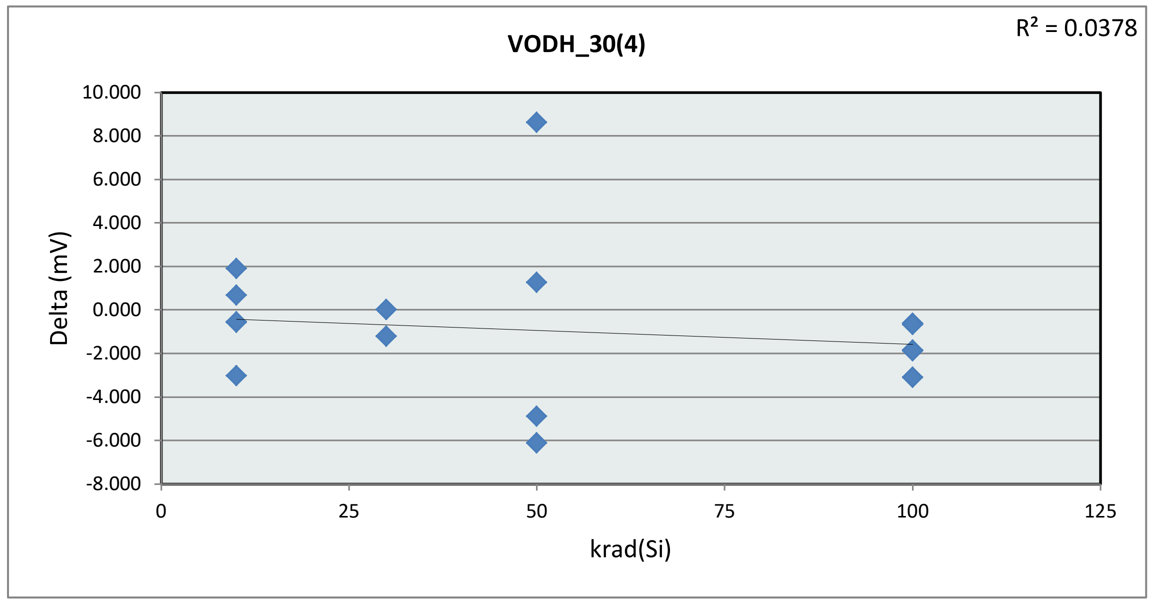
	DVOD_30(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-3.074	-3.816	-2.585	-4.869
Average	-1.618	-2.094	-2.090	-2.092
Max	-0.650	-1.352	-1.349	0.015
UL	25.000	25.000	25.000	25.000

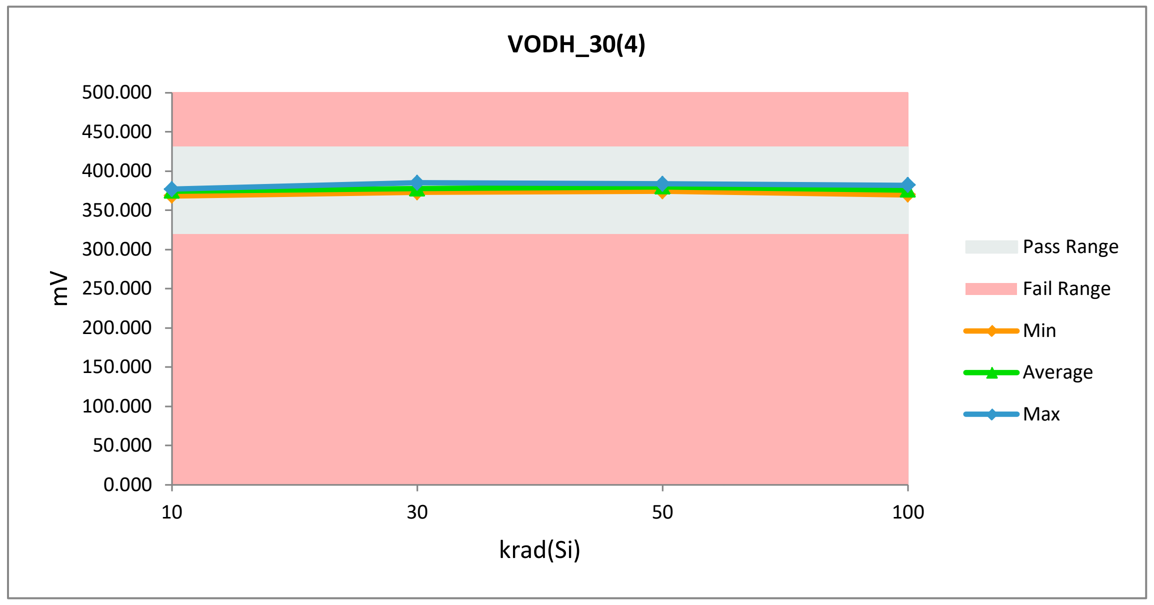


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	371.415	374.434	-3.019
10	2	376.322	375.652	0.670
10	3	367.730	368.313	-0.583
10	4	376.320	376.862	-0.542
10	5	378.781	376.881	1.900
30	1	376.370	376.356	0.014
30	2	377.603	378.811	-1.208
30	3	384.966	384.948	0.018
30	4	371.462	372.674	-1.212
30	5	373.914	373.901	0.013
50	11	378.830	383.720	-4.890
50	12	373.917	380.038	-6.121
50	13	382.515	373.901	8.614
50	14	380.061	378.811	1.250
50	15	376.381	382.493	-6.112
100	22	371.412	373.298	-1.886
100	23	381.234	381.860	-0.626
100	24	373.867	375.740	-1.873
100	25	376.318	376.950	-0.632
100	26	380.004	380.631	-0.627
100	27	376.319	376.956	-0.637
100	28	378.775	379.404	-0.629
100	29	373.864	374.513	-0.649
100	30	370.186	370.859	-0.673
100	31	373.862	376.954	-3.092
100	32	376.320	378.181	-1.861
100	33	375.097	376.967	-1.870
100	34	376.324	376.971	-0.647
100	35	373.857	375.710	-1.853
100	36	377.553	379.421	-1.868
100	37	372.642	374.525	-1.883
100	38	375.096	376.969	-1.873
100	39	368.949	370.823	-1.874
100	41	366.496	369.605	-3.109
100	42	372.638	374.513	-1.875
100	43	368.957	369.626	-0.669
100	44	373.867	376.963	-3.096
	Max	384.966	384.948	8.614
	Average	375.141	376.358	-1.216
	Min	366.496	368.313	-6.121
	Std Dev	4.066	3.842	2.381

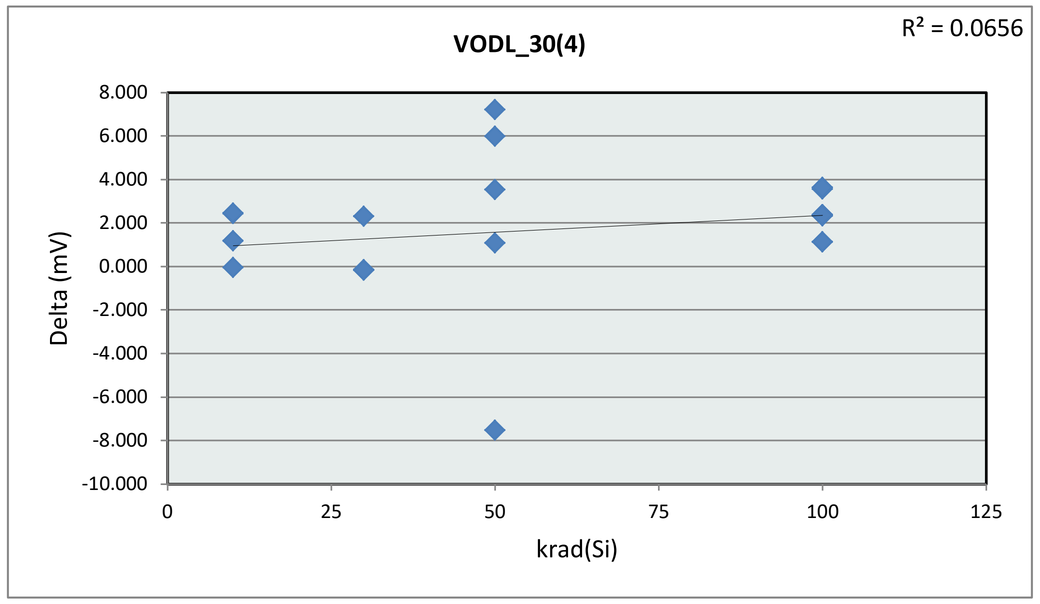


	VODH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	368.313	372.674	373.901	369.605
Average	374.428	377.338	379.793	375.793
Max	376.881	384.948	383.720	381.860
UL	430.000	430.000	430.000	430.000

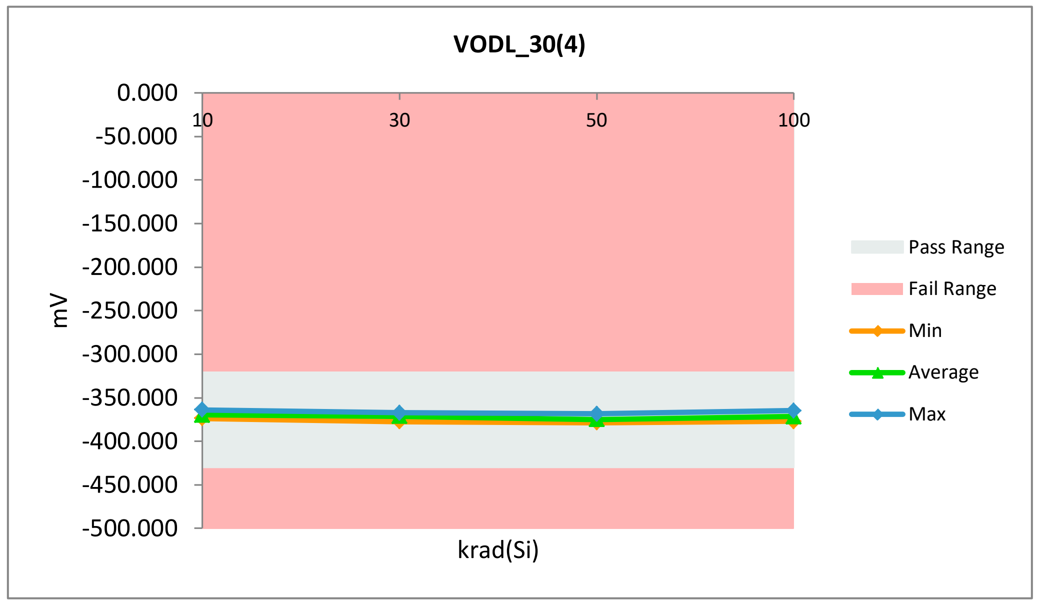


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-365.001	-367.425	2.424
10	2	-371.140	-372.319	1.179
10	3	-361.323	-363.769	2.446
10	4	-372.370	-373.554	1.184
10	5	-372.364	-372.306	-0.058
30	1	-370.039	-369.875	-0.164
30	2	-373.716	-373.557	-0.159
30	3	-377.403	-377.239	-0.164
30	4	-366.353	-368.647	2.294
30	5	-367.584	-367.420	-0.164
50	11	-374.945	-378.466	3.521
50	12	-368.809	-374.784	5.975
50	13	-376.170	-368.648	-7.522
50	14	-377.396	-378.466	1.070
50	15	-367.573	-374.784	7.211
100	22	-365.005	-367.370	2.365
100	23	-374.821	-377.141	2.320
100	24	-371.141	-373.483	2.342
100	25	-371.145	-372.273	1.128
100	26	-373.595	-375.923	2.328
100	27	-371.143	-373.490	2.347
100	28	-374.824	-377.154	2.330
100	29	-368.690	-369.823	1.133
100	30	-362.548	-364.920	2.372
100	31	-367.464	-369.826	2.362
100	32	-373.597	-375.931	2.334
100	33	-373.594	-375.921	2.327
100	34	-368.684	-371.030	2.346
100	35	-369.923	-372.292	2.369
100	36	-371.137	-374.691	3.554
100	37	-368.684	-369.809	1.125
100	38	-372.367	-374.698	2.331
100	39	-363.786	-367.399	3.613
100	41	-362.557	-366.174	3.617
100	42	-368.688	-371.046	2.358
100	43	-362.550	-364.930	2.380
100	44	-367.459	-369.817	2.358
	Max	-361.323	-363.769	7.211
	Average	-369.881	-371.795	1.914
	Min	-377.403	-378.466	-7.522
	Std Dev	4.315	4.023	2.193



	VODL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-373.554	-377.239	-378.466	-377.154
Average	-369.875	-371.348	-375.030	-371.597
Max	-363.769	-367.420	-368.648	-364.920
UL	-320.000	-320.000	-320.000	-320.000



HDR Biased TID Report
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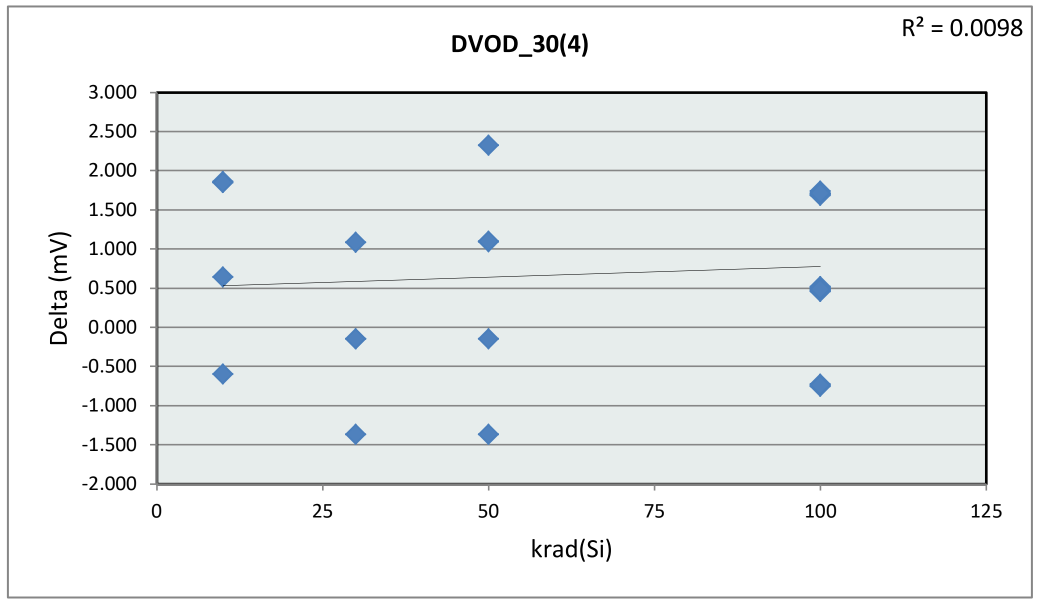
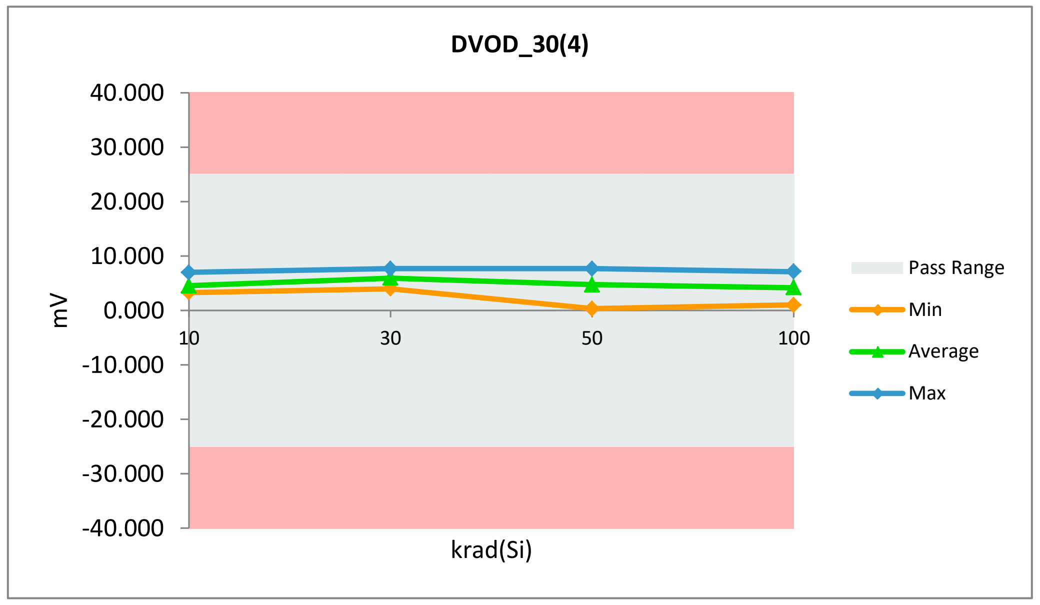
	DVOD_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	6.414	7.010	-0.596
10	2	5.182	3.333	1.849
10	3	6.407	4.545	1.862
10	4	3.950	3.308	0.642
10	5	6.418	4.575	1.843
30	1	6.331	6.481	-0.150
30	2	3.886	5.254	-1.368
30	3	7.563	7.709	-0.146
30	4	5.109	4.027	1.082
30	5	6.330	6.481	-0.151
50	11	3.886	5.254	-1.368
50	12	5.107	5.254	-0.147
50	13	6.345	5.254	1.091
50	14	2.665	0.345	2.320
50	15	8.808	7.709	1.099
100	22	6.407	5.927	0.480
100	23	6.413	4.719	1.694
100	24	2.726	2.258	0.468
100	25	5.173	4.677	0.496
100	26	6.409	4.708	1.701
100	27	5.176	3.466	1.710
100	28	3.951	2.250	1.701
100	29	5.174	4.691	0.483
100	30	7.639	5.939	1.700
100	31	6.398	7.128	-0.730
100	32	2.723	2.250	0.473
100	33	1.503	1.046	0.457
100	34	7.640	5.941	1.699
100	35	3.934	3.418	0.516
100	36	6.416	4.731	1.685
100	37	3.958	4.716	-0.758
100	38	2.729	2.271	0.458
100	39	5.163	3.424	1.739
100	41	3.939	3.432	0.507
100	42	3.949	3.468	0.481
100	43	6.407	4.696	1.711
100	44	6.408	7.147	-0.739
	Max	8.808	7.709	2.320
	Average	5.260	4.563	0.697
	Min	1.503	0.345	-1.368
	Std Dev	1.669	1.789	1.000



	DVOD_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.308	4.027	0.345	1.046
Average	4.554	5.990	4.763	4.196
Max	7.010	7.709	7.709	7.147
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
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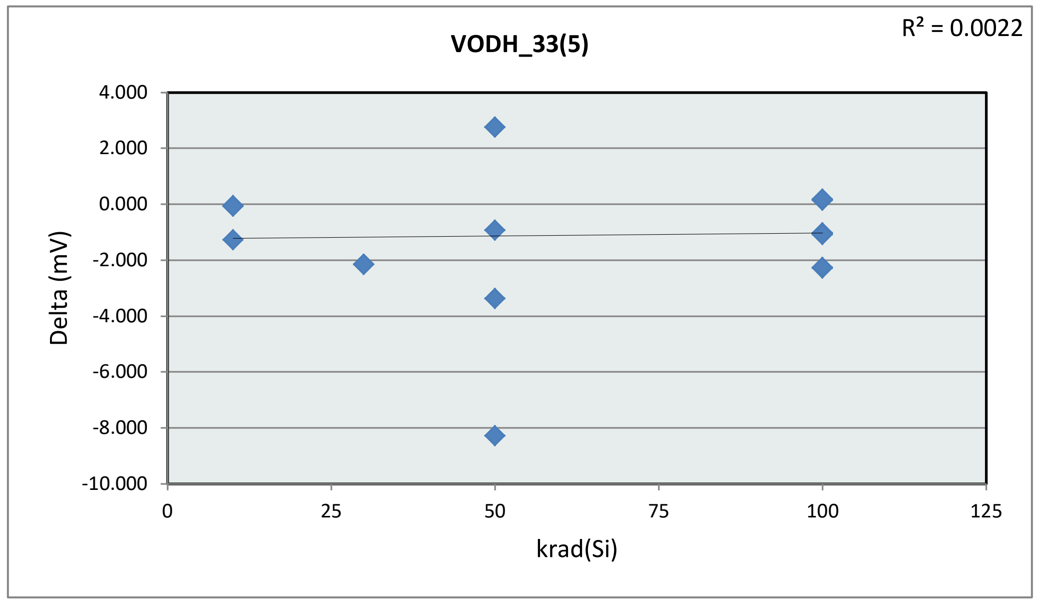
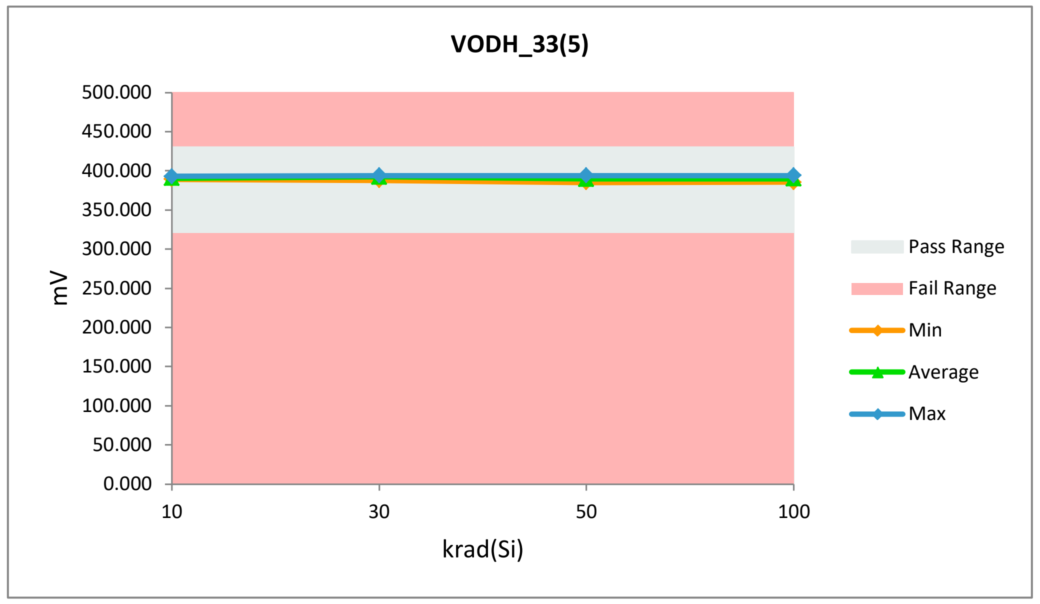
		VODH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	389.258	389.339	-0.081
10	2	391.711	391.777	-0.066
10	3	389.256	389.330	-0.074
10	4	391.710	392.992	-1.282
10	5	389.258	389.339	-0.081
30	1	391.684	393.838	-2.154
30	2	385.547	387.701	-2.154
30	3	391.686	393.840	-2.154
30	4	391.685	393.839	-2.154
30	5	389.228	391.381	-2.153
50	11	385.548	393.838	-8.290
50	12	388.006	385.248	2.758
50	13	391.686	388.934	2.752
50	14	386.774	387.702	-0.928
50	15	389.230	392.613	-3.383
100	22	386.802	389.098	-2.296
100	23	389.256	391.537	-2.281
100	24	392.937	393.974	-1.037
100	25	389.256	389.095	0.161
100	26	390.484	391.539	-1.055
100	27	388.030	387.879	0.151
100	28	390.483	391.530	-1.047
100	29	388.031	389.104	-1.073
100	30	391.710	392.754	-1.044
100	31	390.483	391.538	-1.055
100	32	390.483	391.537	-1.054
100	33	385.575	386.650	-1.075
100	34	389.256	390.317	-1.061
100	35	390.484	391.543	-1.059
100	36	389.256	390.315	-1.059
100	37	389.256	389.089	0.167
100	38	390.482	392.748	-2.266
100	39	388.028	389.092	-1.064
100	41	384.348	385.437	-1.089
100	42	385.576	385.441	0.135
100	43	384.349	385.436	-1.087
100	44	392.938	392.760	0.178
	Max	392.938	393.974	2.758
	Average	389.183	390.274	-1.091
	Min	384.348	385.248	-8.290
	Std Dev	2.349	2.624	1.737

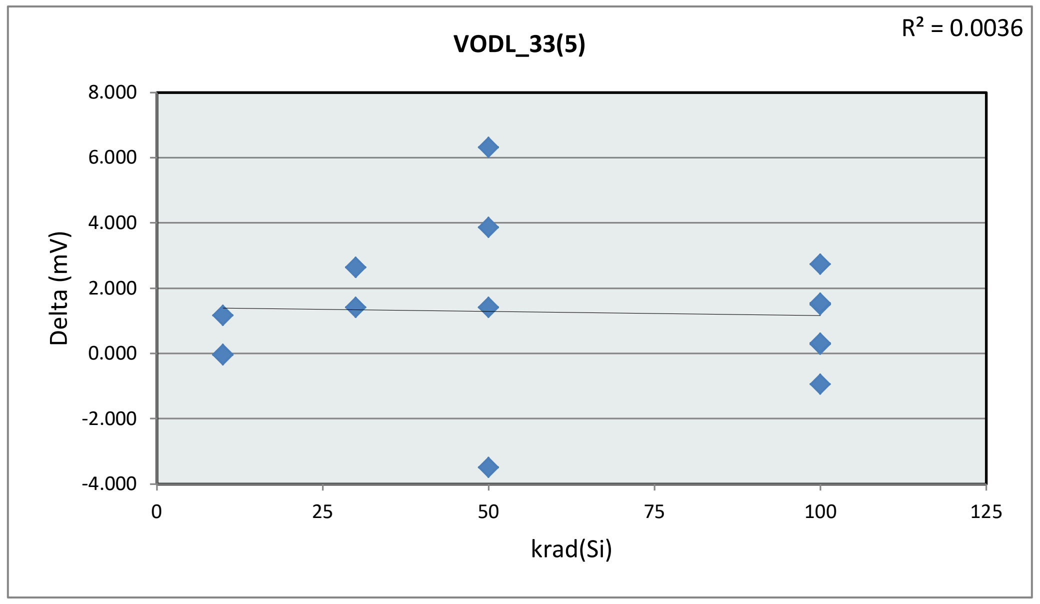


	VODH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	389.330	387.701	385.248	385.436
Average	390.555	392.120	389.667	389.928
Max	392.992	393.840	393.838	393.974
UL	430.000	430.000	430.000	430.000

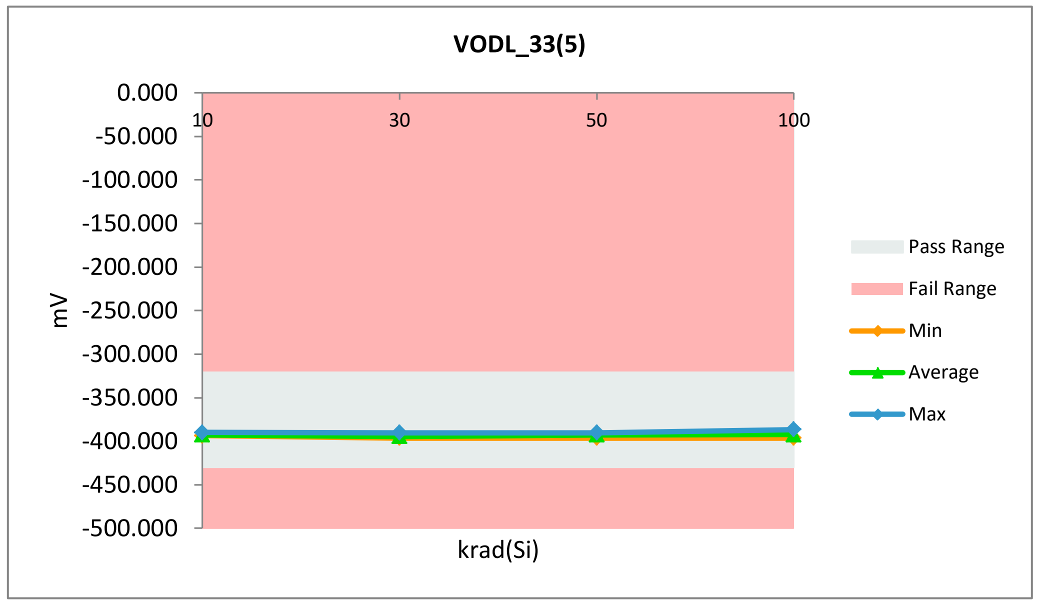


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_33(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-392.484	-393.651	1.167
10	2	-393.712	-393.656	-0.056
10	3	-390.031	-389.996	-0.035
10	4	-392.486	-392.441	-0.045
10	5	-392.484	-393.651	1.167
30	1	-392.573	-395.207	2.634
30	2	-388.893	-390.300	1.407
30	3	-393.799	-396.432	2.633
30	4	-393.800	-395.206	1.406
30	5	-392.575	-395.209	2.634
50	11	-390.118	-396.434	6.316
50	12	-388.888	-390.298	1.410
50	13	-393.799	-390.294	-3.505
50	14	-388.893	-392.753	3.860
50	15	-392.573	-393.977	1.404
100	22	-390.030	-391.545	1.515
100	23	-390.030	-391.549	1.519
100	24	-393.713	-395.220	1.507
100	25	-393.712	-393.990	0.278
100	26	-392.484	-392.768	0.284
100	27	-392.484	-395.206	2.722
100	28	-393.713	-395.219	1.506
100	29	-390.029	-391.538	1.509
100	30	-392.486	-395.218	2.732
100	31	-392.485	-393.991	1.506
100	32	-392.485	-393.992	1.507
100	33	-388.803	-390.327	1.524
100	34	-394.939	-396.433	1.494
100	35	-390.029	-390.321	0.292
100	36	-391.258	-391.549	0.291
100	37	-391.258	-392.775	1.517
100	38	-392.487	-392.782	0.295
100	39	-391.258	-391.551	0.293
100	41	-388.802	-389.096	0.294
100	42	-385.120	-386.650	1.530
100	43	-386.348	-386.655	0.307
100	44	-393.712	-392.769	-0.943
	Max	-385.120	-386.650	6.316
	Average	-391.480	-392.720	1.240
	Min	-394.939	-396.434	-3.505
	Std Dev	2.233	2.495	1.521

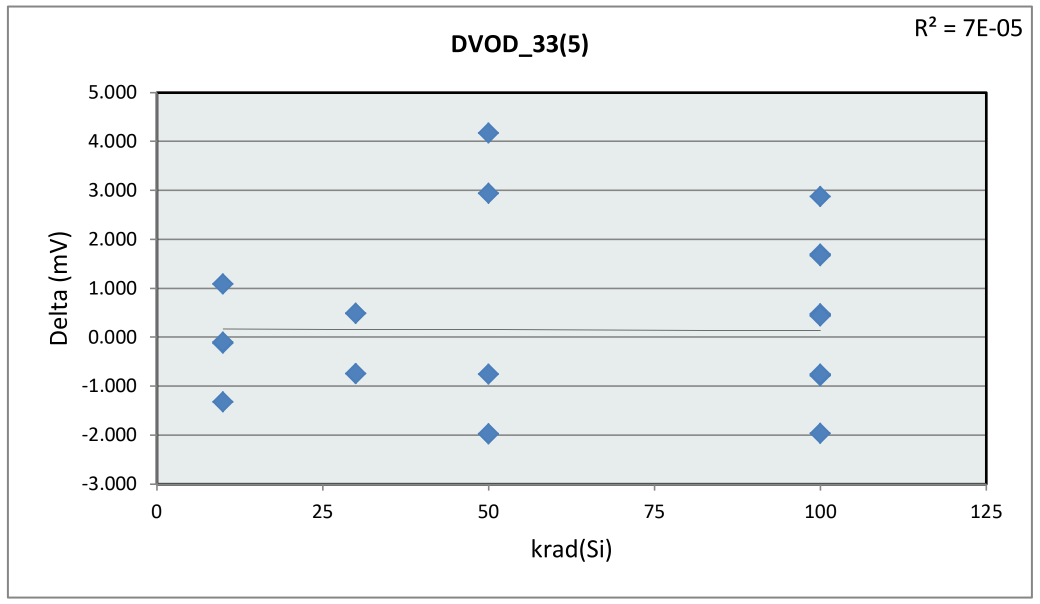


	VODL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-393.656	-396.432	-396.434	-396.433
Average	-392.679	-394.471	-392.751	-392.325
Max	-389.996	-390.300	-390.294	-386.650
UL	-320.000	-320.000	-320.000	-320.000

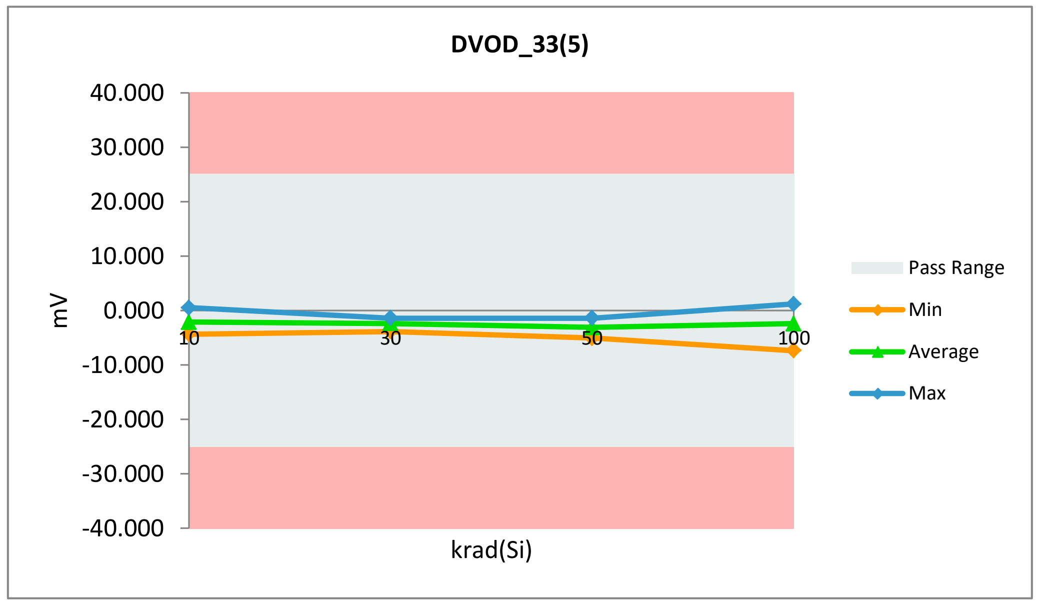


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-3.226	-4.312	1.086
10	2	-2.001	-1.880	-0.121
10	3	-0.775	-0.666	-0.110
10	4	-0.776	0.552	-1.328
10	5	-3.226	-4.313	1.087
30	1	-0.889	-1.369	0.480
30	2	-3.346	-2.599	-0.747
30	3	-2.113	-2.592	0.479
30	4	-2.115	-1.367	-0.748
30	5	-3.347	-3.828	0.481
50	11	-4.570	-2.596	-1.974
50	12	-0.882	-5.050	4.168
50	13	-2.113	-1.360	-0.753
50	14	-2.118	-5.051	2.933
50	15	-3.343	-1.364	-1.979
100	22	-3.227	-2.447	-0.780
100	23	-0.774	-0.012	-0.762
100	24	-0.776	-1.246	0.470
100	25	-4.455	-4.894	0.439
100	26	-2.001	-1.228	-0.773
100	27	-4.454	-7.327	2.873
100	28	-3.230	-3.689	0.459
100	29	-1.998	-2.434	0.436
100	30	-0.776	-2.464	1.688
100	31	-2.001	-2.454	0.453
100	32	-2.002	-2.455	0.453
100	33	-3.229	-3.676	0.447
100	34	-5.683	-6.116	0.433
100	35	0.455	1.222	-0.767
100	36	-2.002	-1.234	-0.768
100	37	-2.002	-3.686	1.684
100	38	-2.005	-0.033	-1.972
100	39	-3.230	-2.459	-0.771
100	41	-4.454	-3.659	-0.795
100	42	0.456	-1.208	1.664
100	43	-1.999	-1.218	-0.781
100	44	-0.774	-0.009	-0.764
	Max	0.456	1.222	4.168
	Average	-2.297	-2.447	0.149
	Min	-5.683	-7.327	-1.979
	Std Dev	1.424	1.883	1.365



	DVOD_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-4.313	-3.828	-5.051	-7.327
Average	-2.124	-2.351	-3.084	-2.397
Max	0.552	-1.367	-1.360	1.222
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
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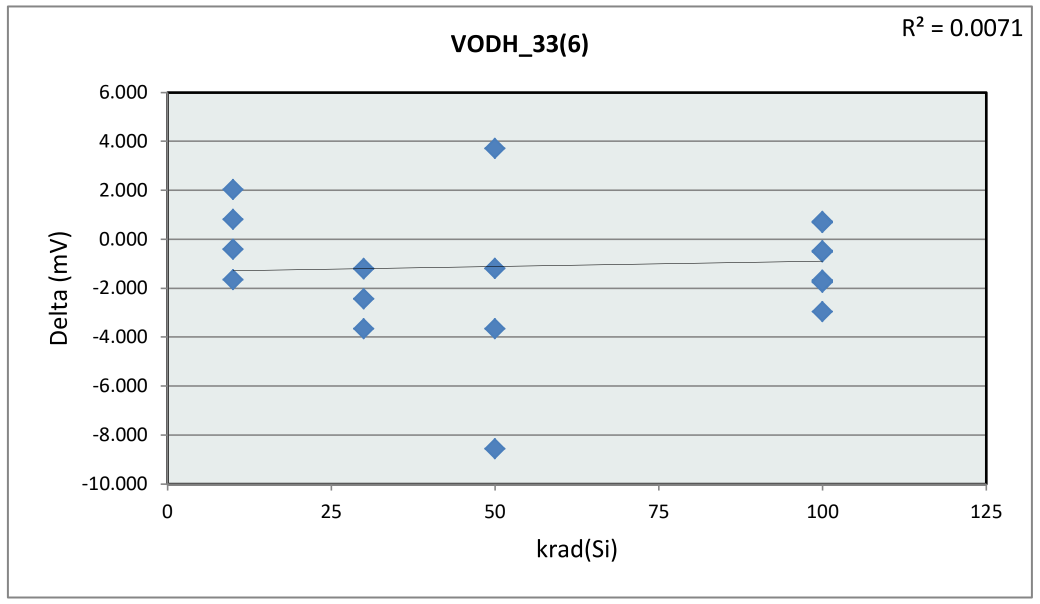
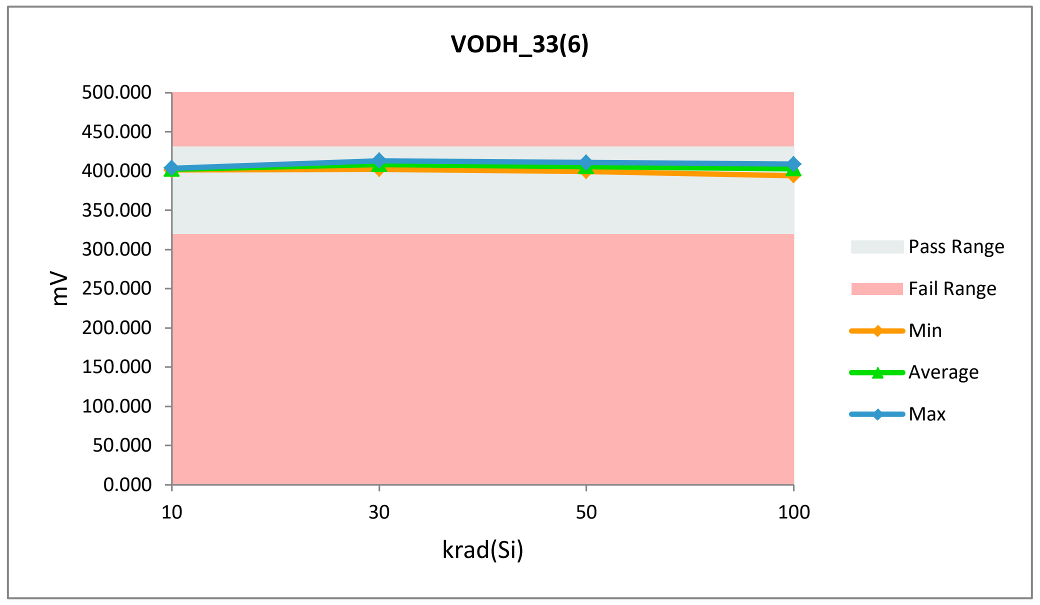
		VODH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	400.862	402.513	-1.651
10	2	403.314	403.727	-0.413
10	3	402.087	401.285	0.802
10	4	400.856	401.271	-0.415
10	5	404.545	402.511	2.034
30	1	407.054	409.494	-2.440
30	2	398.466	402.130	-3.664
30	3	410.738	413.176	-2.438
30	4	405.829	407.040	-1.211
30	5	408.281	409.494	-1.213
50	11	402.147	410.722	-8.575
50	12	405.828	402.130	3.698
50	13	405.833	407.040	-1.207
50	14	398.468	399.676	-1.208
50	15	404.610	408.267	-3.657
100	22	400.859	403.822	-2.963
100	23	398.404	398.933	-0.529
100	24	402.086	402.595	-0.509
100	25	405.765	406.253	-0.488
100	26	404.541	403.820	0.721
100	27	404.538	403.811	0.727
100	28	403.312	405.038	-1.726
100	29	402.084	402.593	-0.509
100	30	403.316	405.053	-1.737
100	31	404.536	405.034	-0.498
100	32	402.084	403.813	-1.729
100	33	392.268	394.042	-1.774
100	34	405.771	406.272	-0.501
100	35	406.986	408.677	-1.691
100	36	403.317	402.612	0.705
100	37	400.861	400.160	0.701
100	38	395.951	395.269	0.682
100	39	404.533	405.017	-0.484
100	41	400.852	402.576	-1.724
100	42	400.857	401.370	-0.513
100	43	400.859	402.599	-1.740
100	44	405.769	406.265	-0.496
	Max	410.738	413.176	3.698
	Average	402.932	403.949	-1.017
	Min	392.268	394.042	-8.575
	Std Dev	3.516	3.893	1.943



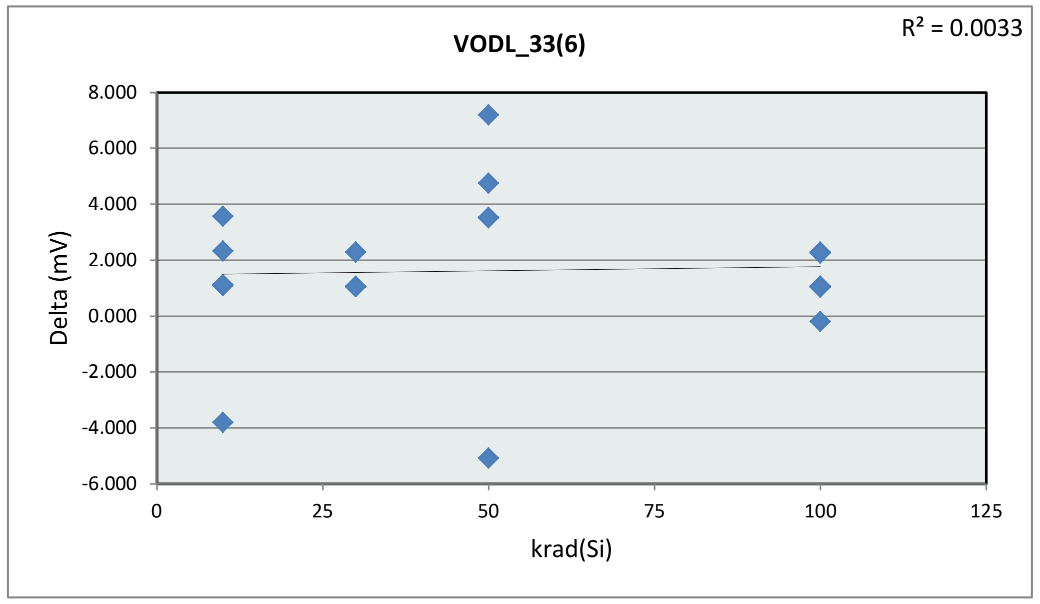
	VODH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	401.271	402.130	399.676	394.042
Average	402.261	408.267	405.567	402.983
Max	403.727	413.176	410.722	408.677
UL	430.000	430.000	430.000	430.000



HDR Biased TID Report
SN55LVCP22A-SP

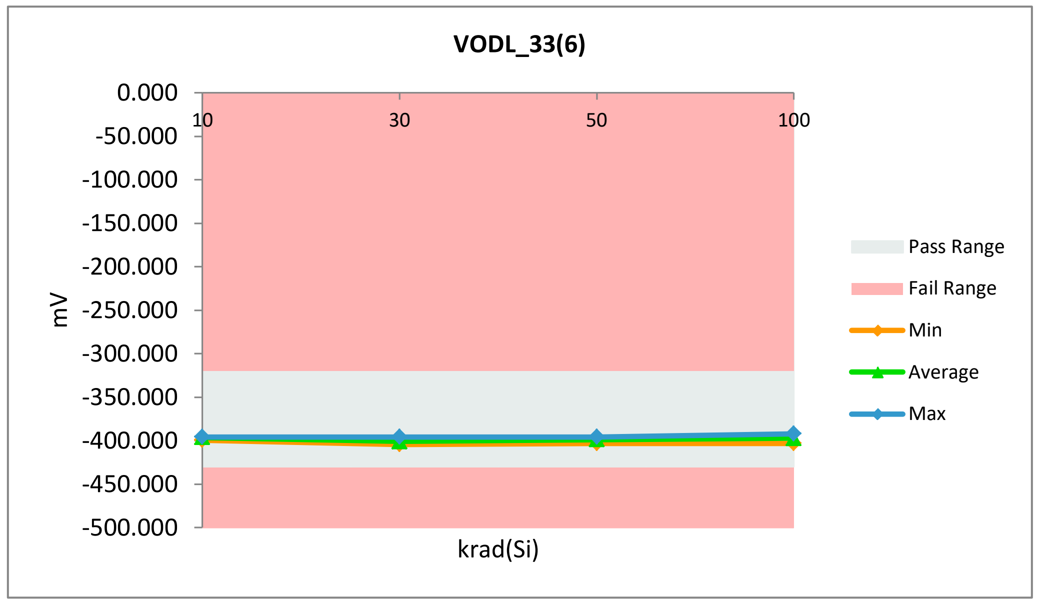
	VODL_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-392.012	-395.564	3.552
10	2	-398.152	-399.239	1.087
10	3	-393.242	-395.571	2.329
10	4	-394.474	-395.584	1.110
10	5	-399.376	-395.558	-3.818
30	1	-400.737	-401.786	1.049
30	2	-394.593	-395.649	1.056
30	3	-401.964	-404.241	2.277
30	4	-399.506	-401.786	2.280
30	5	-399.510	-400.559	1.049
50	11	-395.822	-403.014	7.192
50	12	-400.735	-395.650	-5.085
50	13	-395.820	-400.559	4.739
50	14	-394.591	-398.104	3.513
50	15	-393.360	-396.877	3.517
100	22	-393.244	-395.511	2.267
100	23	-390.789	-391.845	1.056
100	24	-395.698	-397.959	2.261
100	25	-398.157	-399.192	1.035
100	26	-396.925	-397.956	1.031
100	27	-396.928	-399.190	2.262
100	28	-398.155	-400.408	2.253
100	29	-395.701	-396.740	1.039
100	30	-394.468	-396.725	2.257
100	31	-396.930	-399.188	2.258
100	32	-396.928	-399.188	2.260
100	33	-389.561	-391.847	2.286
100	34	-395.696	-397.950	2.254
100	35	-401.845	-402.879	1.034
100	36	-396.922	-396.721	-0.201
100	37	-394.468	-395.505	1.037
100	38	-390.788	-391.842	1.054
100	39	-396.933	-399.203	2.270
100	41	-395.705	-396.757	1.052
100	42	-395.700	-396.742	1.042
100	43	-394.470	-396.734	2.264
100	44	-395.698	-397.957	2.259
	Max	-389.561	-391.842	7.192
	Average	-396.097	-397.778	1.680
	Min	-401.964	-404.241	-5.085
	Std Dev	2.968	2.953	1.974



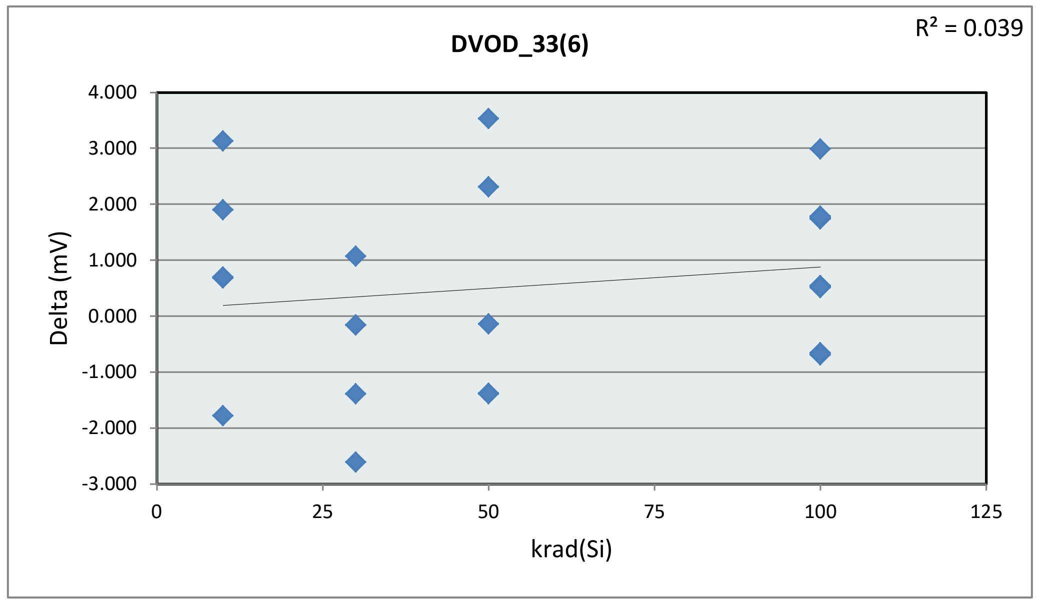
	VODL_33(6)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-399.239	-404.241	-403.014	-402.879
Average	-396.303	-400.804	-398.841	-397.184
Max	-395.558	-395.649	-395.650	-391.842
UL	-320.000	-320.000	-320.000	-320.000

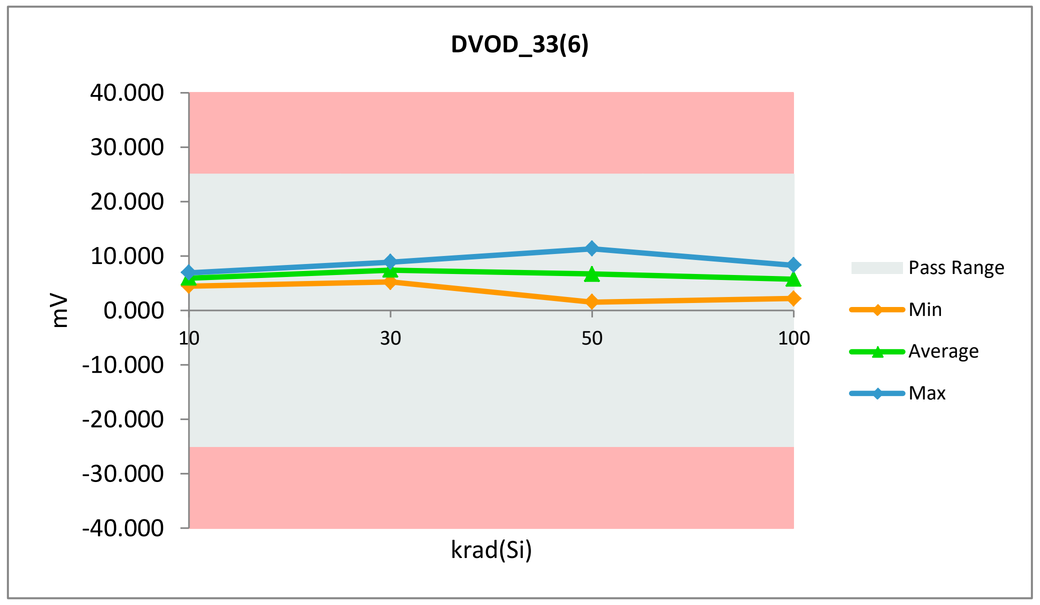


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	8.850	6.950	1.900
10	2	5.162	4.488	0.674
10	3	8.845	5.713	3.132
10	4	6.383	5.687	0.696
10	5	5.170	6.953	-1.783
30	1	6.317	7.708	-1.391
30	2	3.872	6.481	-2.609
30	3	8.774	8.935	-0.161
30	4	6.323	5.253	1.070
30	5	8.771	8.935	-0.164
50	11	6.325	7.708	-1.383
50	12	5.094	6.481	-1.387
50	13	10.012	6.481	3.531
50	14	3.877	1.572	2.305
50	15	11.250	11.390	-0.140
100	22	7.615	8.311	-0.696
100	23	7.615	7.088	0.527
100	24	6.388	4.636	1.752
100	25	7.608	7.061	0.547
100	26	7.615	5.865	1.750
100	27	7.610	4.621	2.989
100	28	5.157	4.630	0.527
100	29	6.383	5.853	0.530
100	30	8.848	8.328	0.520
100	31	7.606	5.846	1.760
100	32	5.156	4.624	0.532
100	33	2.708	2.195	0.513
100	34	10.075	8.322	1.753
100	35	5.141	5.798	-0.657
100	36	6.395	5.891	0.504
100	37	6.393	4.655	1.738
100	38	5.163	3.428	1.735
100	39	7.600	5.813	1.787
100	41	5.147	5.819	-0.672
100	42	5.157	4.628	0.529
100	43	6.390	5.865	0.525
100	44	10.071	8.307	1.764
	Max	11.250	11.390	3.531
	Average	6.834	6.171	0.663
	Min	2.708	1.572	-2.609
	Std Dev	1.947	1.918	1.400

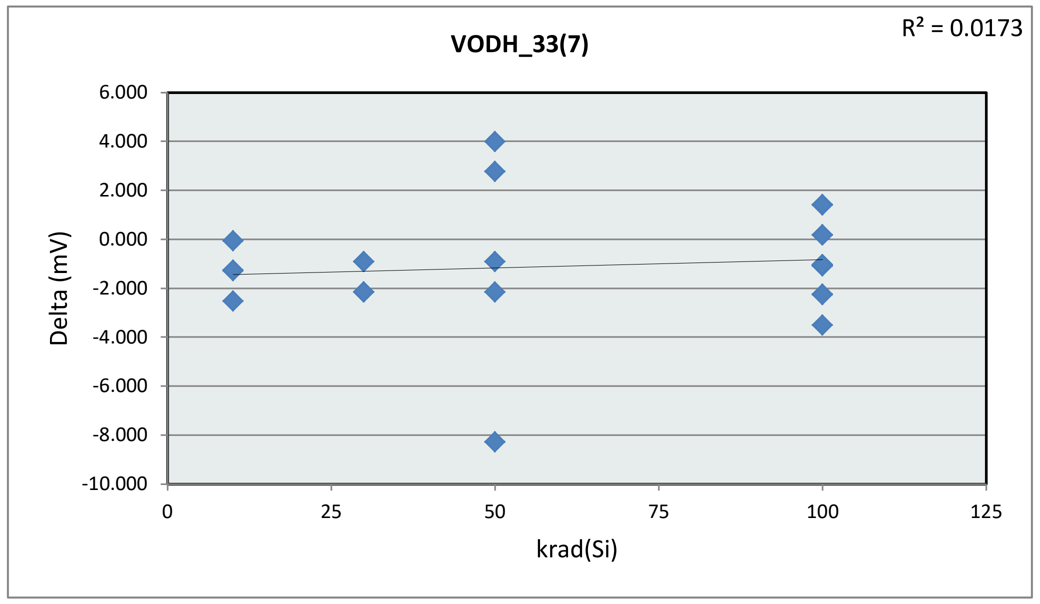


	DVOD_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	4.488	5.253	1.572	2.195
Average	5.958	7.462	6.726	5.799
Max	6.953	8.935	11.390	8.328
UL	25.000	25.000	25.000	25.000

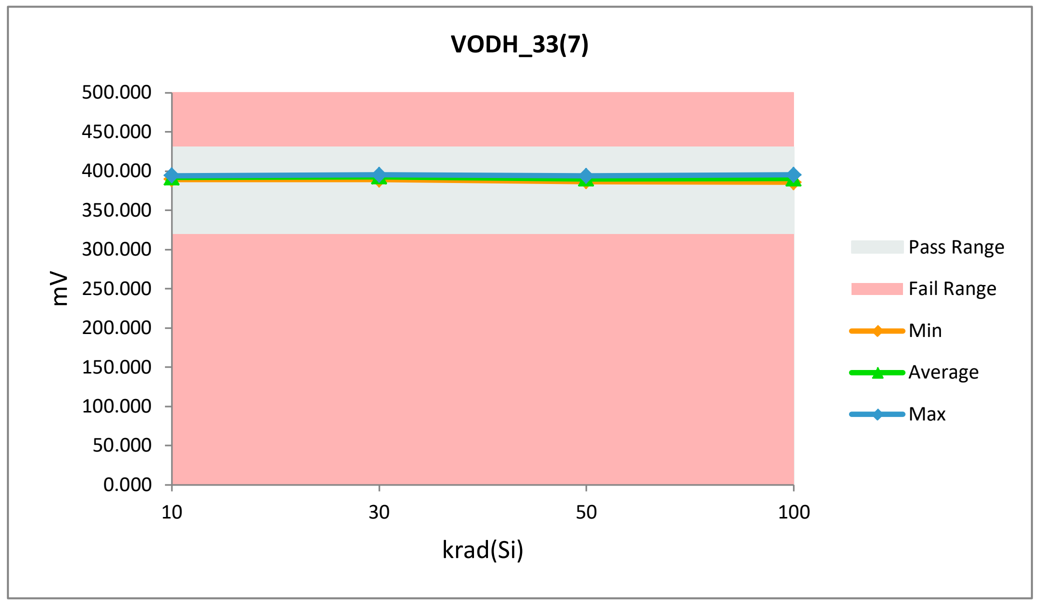


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	389.257	391.780	-2.523
10	2	391.710	392.995	-1.285
10	3	389.255	390.549	-1.294
10	4	392.936	394.211	-1.275
10	5	389.257	389.336	-0.079
30	1	394.138	395.064	-0.926
30	2	386.773	388.926	-2.153
30	3	392.912	395.065	-2.153
30	4	391.684	393.837	-2.153
30	5	390.454	391.380	-0.926
50	11	385.547	393.836	-8.289
50	12	389.232	386.474	2.758
50	13	391.685	387.705	3.980
50	14	388.000	388.927	-0.927
50	15	390.456	392.611	-2.155
100	22	386.802	390.316	-3.514
100	23	391.710	391.533	0.177
100	24	392.936	395.192	-2.256
100	25	389.256	389.092	0.164
100	26	391.711	392.757	-1.046
100	27	388.029	389.097	-1.068
100	28	390.482	390.305	0.177
100	29	390.485	390.322	0.163
100	30	391.709	393.972	-2.263
100	31	391.710	392.756	-1.046
100	32	390.483	391.533	-1.050
100	33	386.801	387.867	-1.066
100	34	389.256	390.313	-1.057
100	35	390.484	391.539	-1.055
100	36	390.483	389.089	1.394
100	37	389.255	390.307	-1.052
100	38	392.936	391.523	1.413
100	39	389.255	390.310	-1.055
100	41	384.348	385.434	-1.086
100	42	385.576	386.659	-1.083
100	43	385.575	386.654	-1.079
100	44	392.938	393.978	-1.040
	Max	394.138	395.192	3.980
	Average	389.879	390.898	-1.020
	Min	384.348	385.434	-8.289
	Std Dev	2.447	2.604	1.881



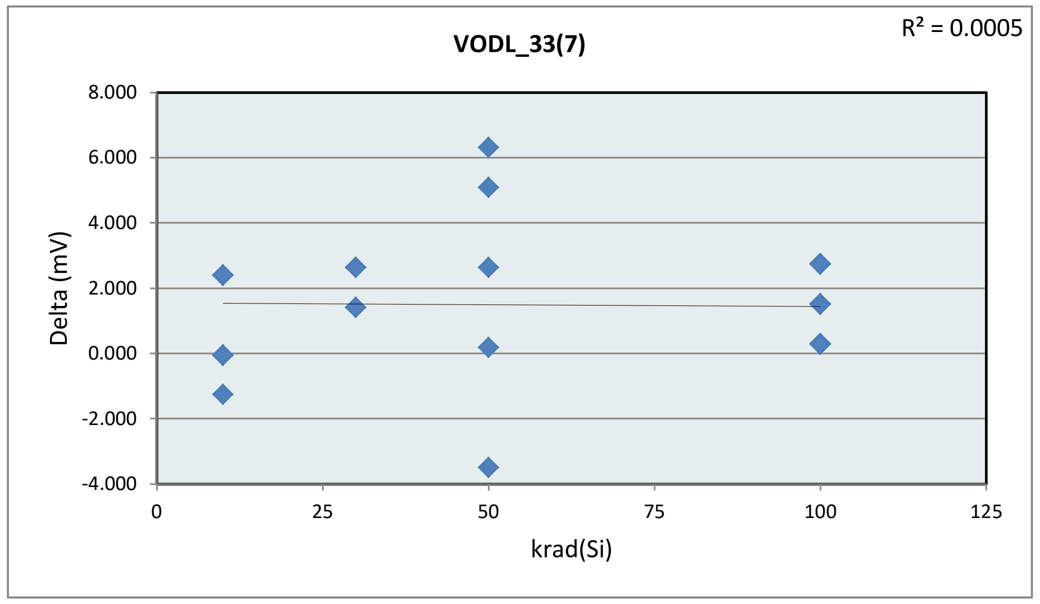
	VODH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	389.336	388.926	386.474	385.434
Average	391.774	392.854	389.911	390.479
Max	394.211	395.065	393.836	395.192
UL	430.000	430.000	430.000	430.000



HDR Biased TID Report
SN55LVCP22A-SP

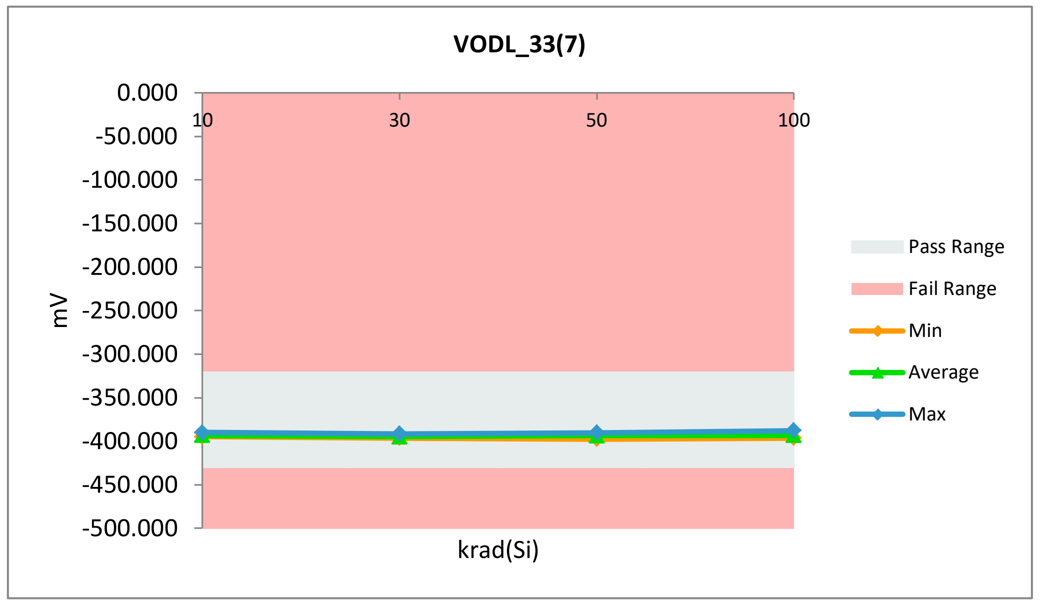
	VODL_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	-392.484	-394.875	2.391
10	2	-392.485	-394.881	2.396
10	3	-391.259	-389.999	-1.260
10	4	-393.714	-393.665	-0.049
10	5	-393.711	-393.654	-0.057
30	1	-392.575	-395.208	2.633
30	2	-388.894	-391.529	2.635
30	3	-393.800	-396.434	2.634
30	4	-395.029	-396.435	1.406
30	5	-393.804	-395.211	1.407
50	11	-391.347	-397.663	6.316
50	12	-390.116	-390.299	0.183
50	13	-393.800	-390.296	-3.504
50	14	-388.894	-393.982	5.088
50	15	-392.574	-395.207	2.633
100	22	-391.258	-392.770	1.512
100	23	-390.031	-392.774	2.743
100	24	-393.714	-396.445	2.731
100	25	-393.712	-395.215	1.503
100	26	-393.712	-393.993	0.281
100	27	-393.712	-395.210	1.498
100	28	-394.941	-396.444	1.503
100	29	-391.257	-391.541	0.284
100	30	-393.713	-396.444	2.731
100	31	-392.486	-393.995	1.509
100	32	-391.258	-393.996	2.738
100	33	-388.804	-391.553	2.749
100	34	-396.167	-396.437	0.270
100	35	-391.257	-392.769	1.512
100	36	-392.486	-392.774	0.288
100	37	-392.486	-392.778	0.292
100	38	-392.487	-395.228	2.741
100	39	-391.259	-391.554	0.295
100	41	-390.030	-390.321	0.291
100	42	-387.575	-387.875	0.300
100	43	-387.576	-389.101	1.525
100	44	-393.713	-393.995	0.282
	Max	-387.575	-387.875	6.316
	Average	-392.111	-393.582	1.471
	Min	-396.167	-397.663	-3.504
	Std Dev	2.066	2.377	1.703



	VODL_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

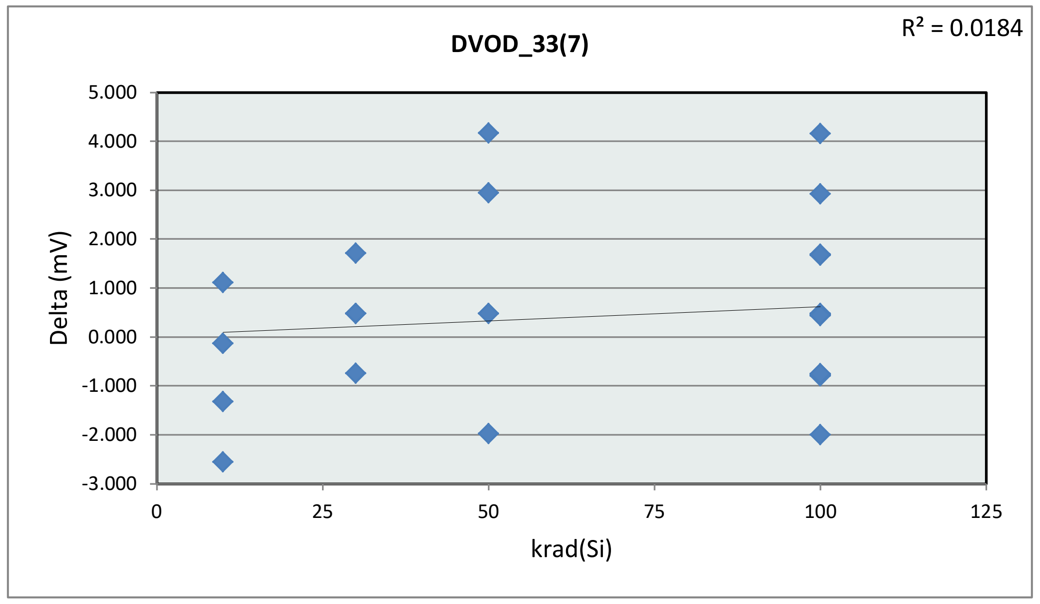
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-394.881	-396.435	-397.663	-396.445
Average	-393.415	-394.963	-393.489	-393.328
Max	-389.999	-391.529	-390.296	-387.875
UL	-320.000	-320.000	-320.000	-320.000



HDR Biased TID Report
SN55LVCP22A-SP

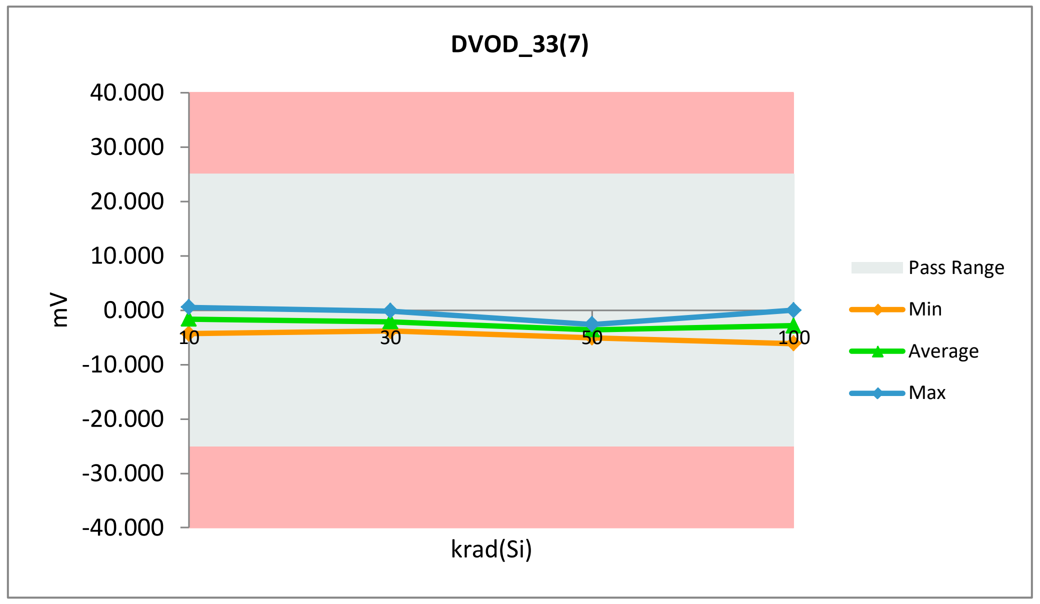
	DVOD_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-3.227	-3.096	-0.131
10	2	-0.775	-1.886	1.111
10	3	-2.004	0.550	-2.554
10	4	-0.777	0.546	-1.324
10	5	-4.454	-4.318	-0.136
30	1	1.563	-0.145	1.708
30	2	-2.121	-2.602	0.481
30	3	-0.889	-1.369	0.480
30	4	-3.345	-2.598	-0.747
30	5	-3.350	-3.831	0.481
50	11	-5.800	-3.827	-1.973
50	12	-0.884	-3.826	2.942
50	13	-2.115	-2.590	0.475
50	14	-0.894	-5.054	4.160
50	15	-2.118	-2.595	0.477
100	22	-4.456	-2.454	-2.002
100	23	1.679	-1.241	2.920
100	24	-0.777	-1.254	0.477
100	25	-4.456	-6.123	1.667
100	26	-2.002	-1.236	-0.766
100	27	-5.682	-6.113	0.431
100	28	-4.459	-6.140	1.681
100	29	-0.772	-1.219	0.447
100	30	-2.004	-2.472	0.468
100	31	-0.776	-1.239	0.463
100	32	-0.776	-2.463	1.687
100	33	-2.003	-3.686	1.683
100	34	-6.911	-6.124	-0.787
100	35	-0.773	-1.229	0.456
100	36	-2.003	-3.685	1.682
100	37	-3.231	-2.471	-0.760
100	38	0.449	-3.705	4.154
100	39	-2.004	-1.244	-0.760
100	41	-5.682	-4.887	-0.795
100	42	-1.999	-1.217	-0.782
100	43	-2.000	-2.447	0.447
100	44	-0.775	-0.017	-0.758
	Max	1.679	0.550	4.160
	Average	-2.233	-2.684	0.451
	Min	-6.911	-6.140	-2.554
	Std Dev	1.989	1.838	1.546



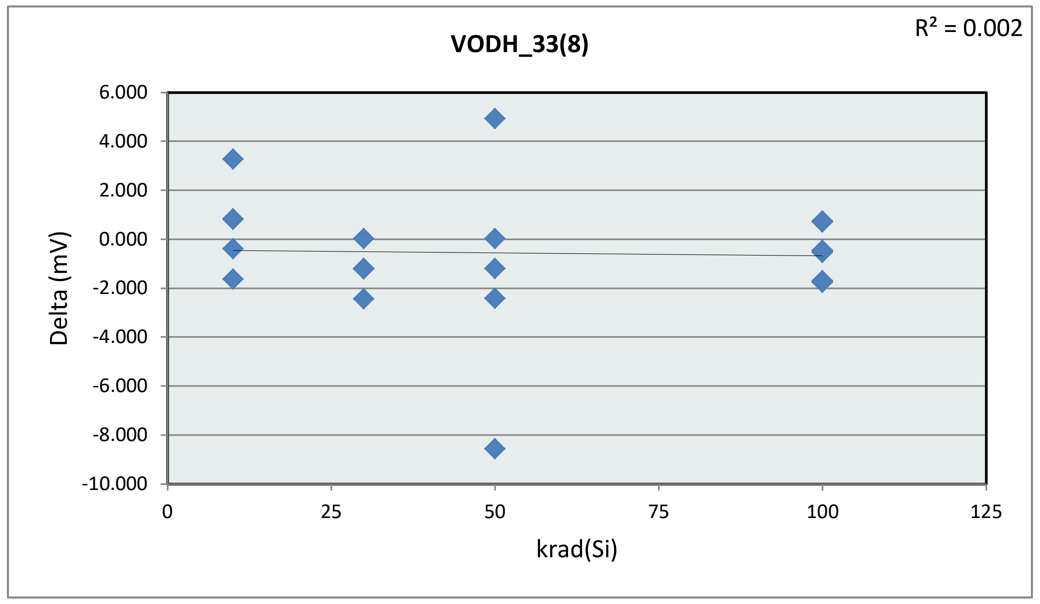
	DVOD_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-4.318	-3.831	-5.054	-6.140
Average	-1.641	-2.109	-3.578	-2.848
Max	0.550	-0.145	-2.590	-0.017
UL	25.000	25.000	25.000	25.000

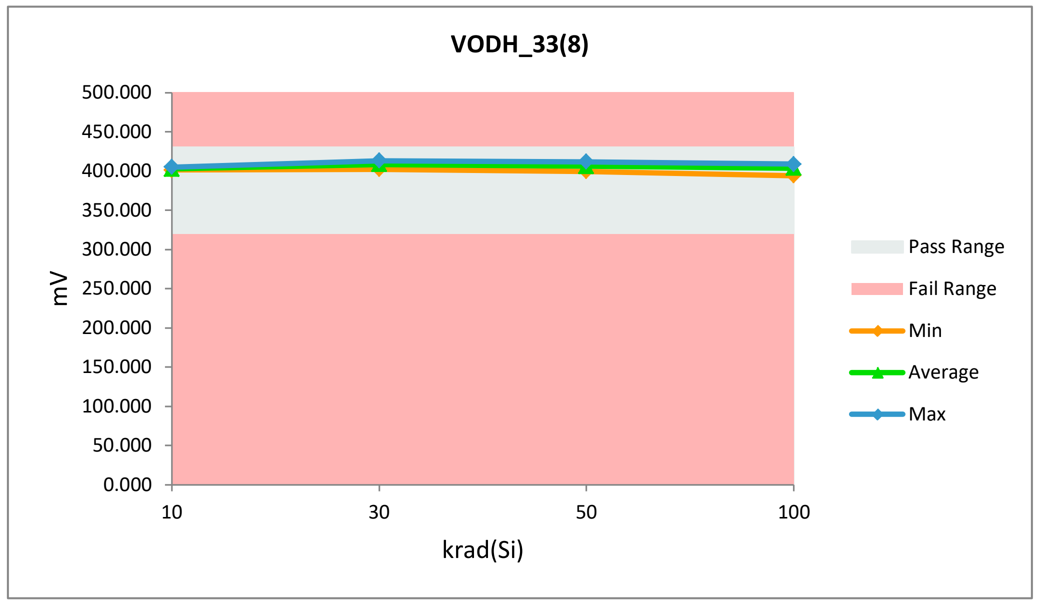


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	402.088	403.729	-1.641
10	2	404.539	404.943	-0.404
10	3	402.085	401.275	0.810
10	4	402.081	401.264	0.817
10	5	405.771	402.504	3.267
30	1	408.280	409.494	-1.214
30	2	399.691	402.130	-2.439
30	3	411.964	413.176	-1.212
30	4	407.055	408.267	-1.212
30	5	409.507	409.494	0.013
50	11	403.373	411.949	-8.576
50	12	408.282	403.358	4.924
50	13	407.058	408.267	-1.209
50	14	399.694	399.676	0.018
50	15	404.608	407.040	-2.432
100	22	400.856	402.593	-1.737
100	23	399.629	398.924	0.705
100	24	402.083	403.811	-1.728
100	25	405.762	407.467	-1.705
100	26	404.538	405.036	-0.498
100	27	404.536	405.024	-0.488
100	28	405.764	405.028	0.736
100	29	404.536	403.811	0.725
100	30	403.314	405.045	-1.731
100	31	404.534	405.026	-0.492
100	32	403.309	403.805	-0.496
100	33	392.266	394.035	-1.769
100	34	406.995	407.486	-0.491
100	35	408.210	408.669	-0.459
100	36	404.542	405.049	-0.507
100	37	400.859	401.376	-0.517
100	38	395.948	396.485	-0.537
100	39	404.530	405.009	-0.479
100	41	402.078	402.569	-0.491
100	42	402.082	402.586	-0.504
100	43	403.312	402.591	0.721
100	44	405.766	406.259	-0.493
	Max	411.964	413.176	4.924
	Average	403.825	404.439	-0.614
	Min	392.266	394.035	-8.576
	Std Dev	3.696	3.880	1.949

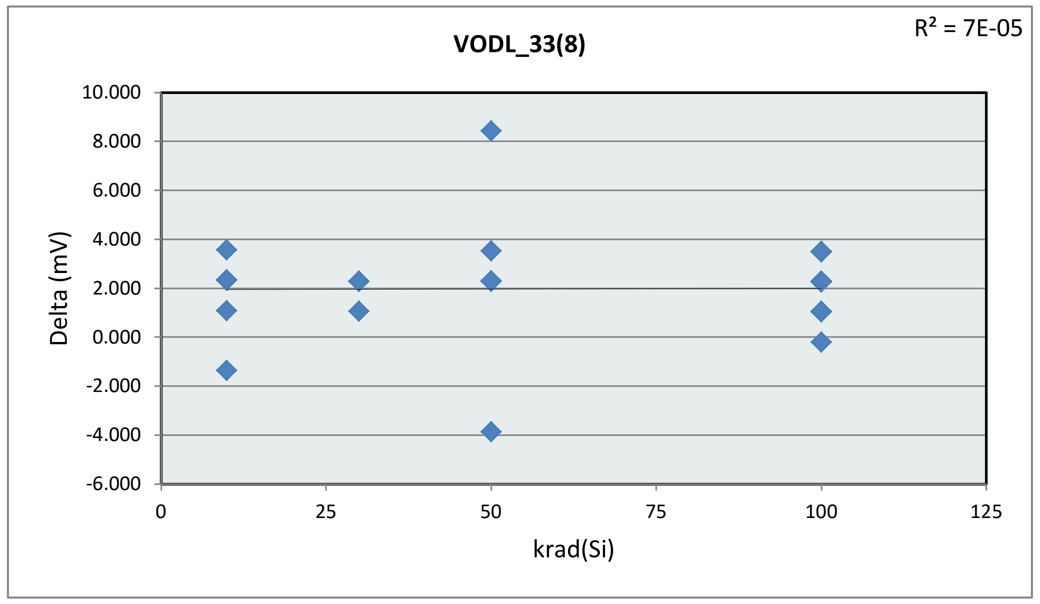


	VODH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	401.264	402.130	399.676	394.035
Average	402.743	408.512	406.058	403.531
Max	404.943	413.176	411.949	408.669
UL	430.000	430.000	430.000	430.000

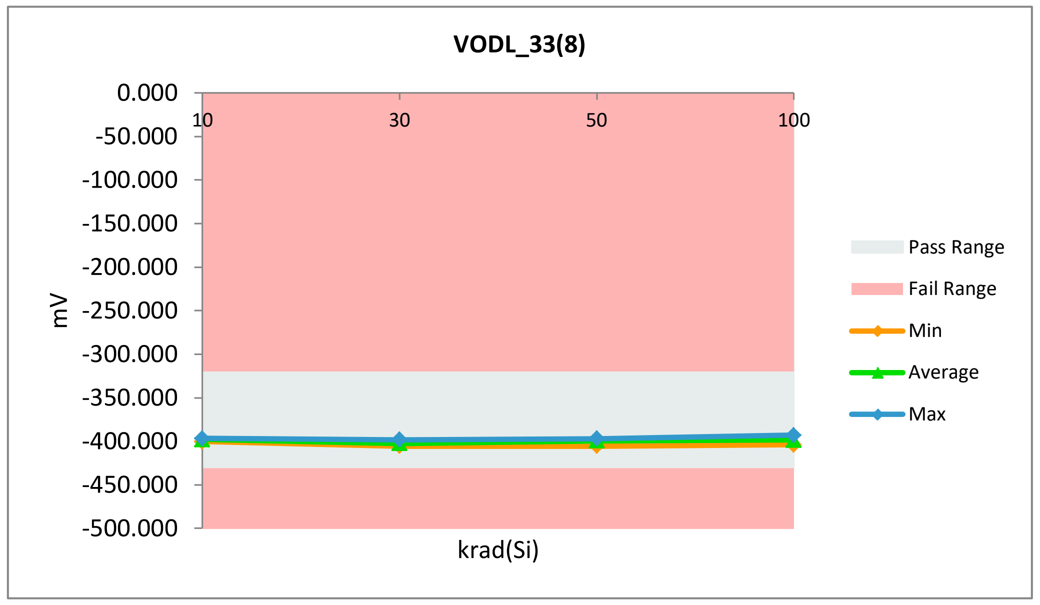


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_33(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-393.242	-396.793	3.551
10	2	-399.382	-400.467	1.085
10	3	-394.472	-396.802	2.330
10	4	-394.476	-396.815	2.339
10	5	-399.378	-398.010	-1.368
30	1	-400.739	-403.014	2.275
30	2	-395.823	-398.104	2.281
30	3	-403.193	-405.469	2.276
30	4	-400.735	-403.014	2.279
30	5	-401.967	-403.014	1.047
50	11	-397.052	-405.469	8.417
50	12	-400.737	-396.877	-3.860
50	13	-398.277	-400.559	2.282
50	14	-394.593	-398.104	3.511
50	15	-394.589	-396.877	2.288
100	22	-393.246	-396.740	3.494
100	23	-392.018	-394.299	2.281
100	24	-396.928	-400.411	3.483
100	25	-399.386	-400.423	1.037
100	26	-398.155	-399.186	1.031
100	27	-399.385	-400.421	1.036
100	28	-400.612	-401.638	1.026
100	29	-395.703	-397.969	2.266
100	30	-394.471	-397.956	3.485
100	31	-398.160	-400.419	2.259
100	32	-398.157	-400.417	2.260
100	33	-390.791	-393.076	2.285
100	34	-396.926	-399.181	2.255
100	35	-403.075	-404.109	1.034
100	36	-398.151	-397.952	-0.199
100	37	-394.471	-396.736	2.265
100	38	-390.790	-393.070	2.280
100	39	-399.390	-400.434	1.044
100	41	-396.934	-397.988	1.054
100	42	-395.702	-397.971	2.269
100	43	-395.700	-397.965	2.265
100	44	-396.928	-399.186	2.258
	Max	-390.790	-393.070	8.417
	Average	-397.128	-399.106	1.978
	Min	-403.193	-405.469	-3.860
	Std Dev	3.177	2.965	1.769



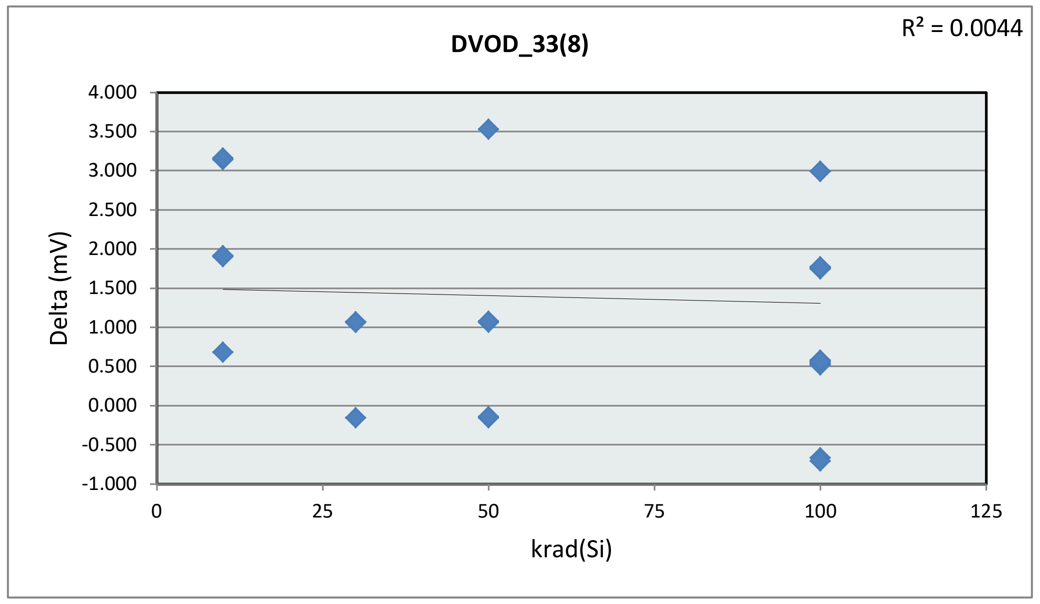
	VODL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-400.467	-405.469	-405.469	-404.109
Average	-397.777	-402.523	-399.577	-398.525
Max	-396.793	-398.104	-396.877	-393.070
UL	-320.000	-320.000	-320.000	-320.000



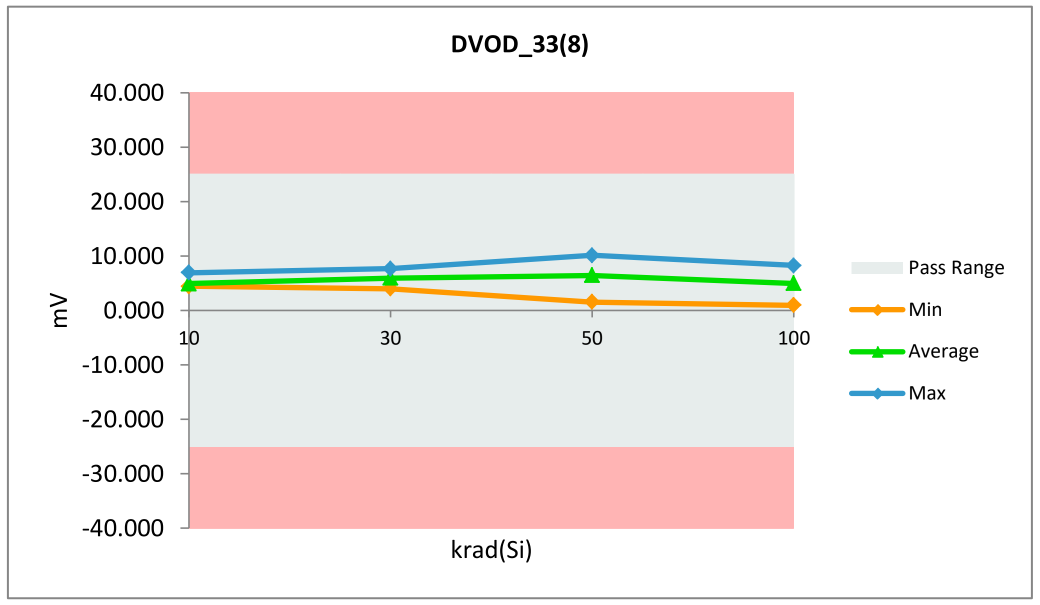
HDR Biased TID Report
SN55LVCP22A-SP

	DVOD_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	8.846	6.936	1.910
10	2	5.158	4.475	0.683
10	3	7.612	4.473	3.139
10	4	7.605	4.449	3.156
10	5	6.393	4.494	1.899
30	1	7.541	6.480	1.061
30	2	3.868	4.026	-0.158
30	3	8.771	7.708	1.063
30	4	6.320	5.253	1.067
30	5	7.540	6.480	1.060
50	11	6.322	6.480	-0.158
50	12	7.546	6.481	1.065
50	13	8.781	7.708	1.073
50	14	5.101	1.572	3.529
50	15	10.019	10.163	-0.144
100	22	7.610	5.853	1.757
100	23	7.610	4.624	2.986
100	24	5.155	3.399	1.756
100	25	6.376	7.044	-0.668
100	26	6.383	5.849	0.534
100	27	5.150	4.604	0.546
100	28	5.152	3.390	1.762
100	29	8.833	5.842	2.991
100	30	8.843	7.090	1.753
100	31	6.374	4.607	1.767
100	32	5.152	3.388	1.764
100	33	1.475	0.959	0.516
100	34	10.069	8.305	1.764
100	35	5.135	4.560	0.575
100	36	6.391	7.097	-0.706
100	37	6.388	4.640	1.748
100	38	5.158	3.415	1.743
100	39	5.140	4.575	0.565
100	41	5.143	4.581	0.562
100	42	6.380	4.615	1.765
100	43	7.612	4.626	2.986
100	44	8.839	7.073	1.766
	Max	10.069	10.163	3.529
	Average	6.697	5.333	1.364
	Min	1.475	0.959	-0.706
	Std Dev	1.796	1.841	1.074



	DVOD_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	4.449	4.026	1.572	0.959
Average	4.965	5.989	6.481	5.006
Max	6.936	7.708	10.163	8.305
UL	25.000	25.000	25.000	25.000



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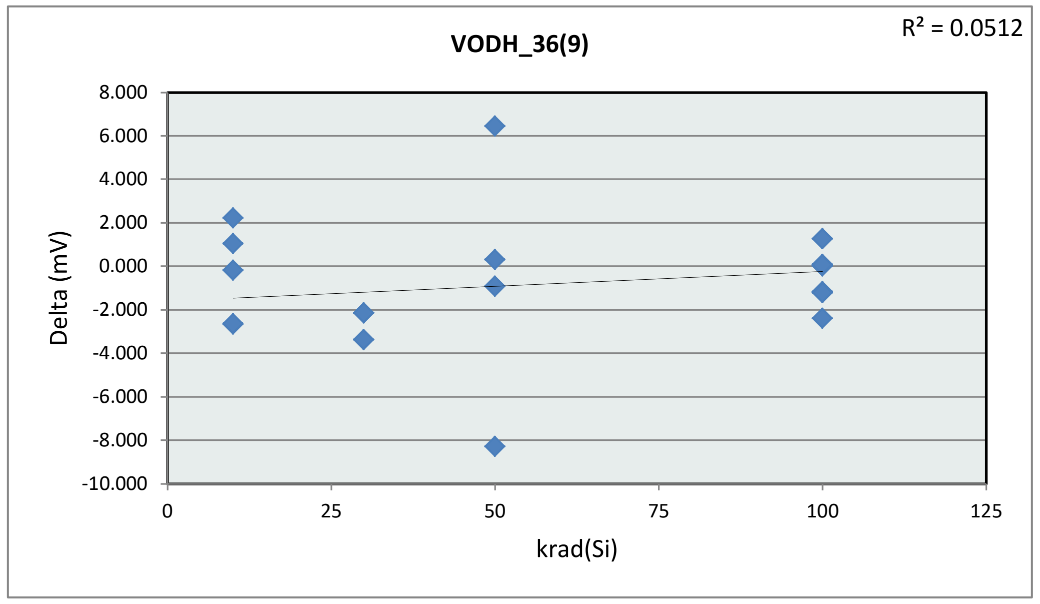
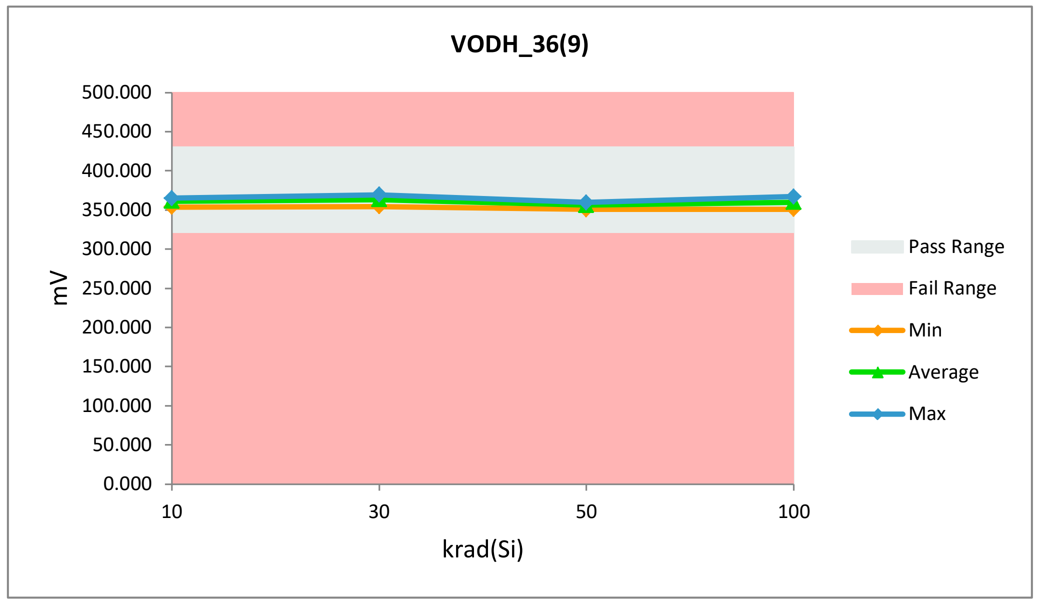
	VODH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	358.575	361.236	-2.661
10	2	362.255	364.894	-2.639
10	3	364.709	364.891	-0.182
10	4	362.254	361.223	1.031
10	5	356.121	353.905	2.216
30	1	363.451	366.835	-3.384
30	2	352.404	354.562	-2.158
30	3	357.316	359.473	-2.157
30	4	367.134	369.290	-2.156
30	5	363.449	366.833	-3.384
50	11	351.178	359.471	-8.293
50	12	357.318	350.883	6.435
50	13	357.316	358.250	-0.934
50	14	353.632	354.563	-0.931
50	15	357.315	357.020	0.295
100	22	357.347	358.543	-1.196
100	23	357.346	358.537	-1.191
100	24	363.482	364.640	-1.158
100	25	357.347	357.318	0.029
100	26	359.801	358.541	1.260
100	27	354.893	356.101	-1.208
100	28	359.800	359.752	0.048
100	29	358.576	358.551	0.025
100	30	367.163	367.085	0.078
100	31	363.483	365.870	-2.387
100	32	361.028	360.981	0.047
100	33	351.210	351.207	0.003
100	34	359.801	358.540	1.261
100	35	365.938	365.875	0.063
100	36	357.346	356.093	1.253
100	37	362.255	362.199	0.056
100	38	361.027	360.971	0.056
100	39	365.937	365.867	0.070
100	41	354.893	356.104	-1.211
100	42	353.666	353.665	0.001
100	43	359.802	359.769	0.033
100	44	363.483	363.427	0.056
	Max	367.163	369.290	6.435
	Average	359.461	360.080	-0.619
	Min	351.178	350.883	-8.293
	Std Dev	4.357	4.705	2.188



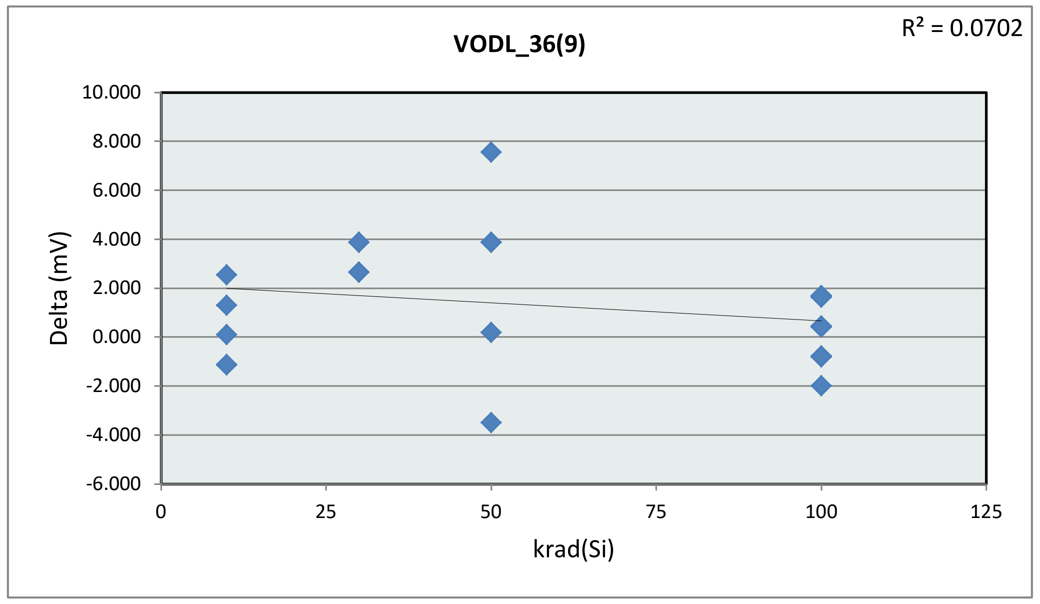
	VODH_36(9)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	430	mV
Min Limit	320	mV

krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	353.905	354.562	350.883	351.207
Average	361.230	363.399	356.037	359.983
Max	364.894	369.290	359.471	367.085
UL	430.000	430.000	430.000	430.000

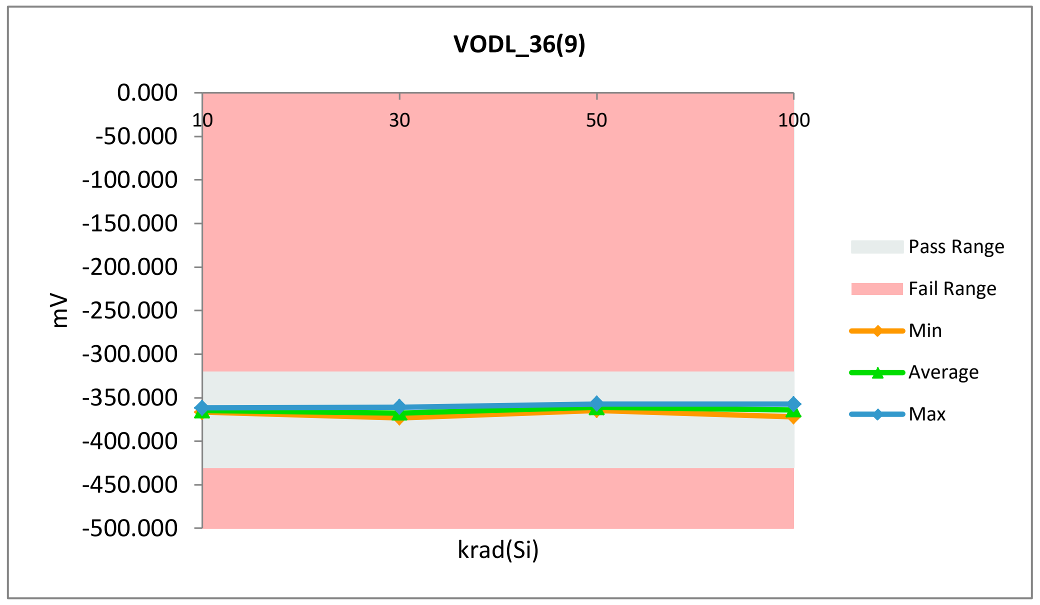


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-364.259	-366.787	2.528
10	2	-365.488	-366.793	1.305
10	3	-366.716	-365.575	-1.141
10	4	-363.035	-363.135	0.100
10	5	-363.032	-361.902	-1.130
30	1	-365.577	-368.216	2.639
30	2	-356.987	-360.855	3.868
30	3	-361.894	-364.533	2.639
30	4	-370.486	-373.124	2.638
30	5	-368.034	-371.900	3.866
50	11	-356.986	-364.536	7.550
50	12	-360.664	-357.172	-3.492
50	13	-358.212	-362.076	3.864
50	14	-356.987	-360.854	3.867
50	15	-360.668	-360.852	0.184
100	22	-363.033	-364.681	1.648
100	23	-355.670	-357.357	1.687
100	24	-365.489	-367.136	1.647
100	25	-365.488	-365.906	0.418
100	26	-360.579	-361.018	0.439
100	27	-363.033	-364.680	1.647
100	28	-365.489	-364.693	-0.796
100	29	-361.805	-361.008	-0.797
100	30	-370.398	-372.020	1.622
100	31	-366.715	-368.349	1.634
100	32	-363.034	-364.686	1.652
100	33	-355.670	-357.356	1.686
100	34	-369.170	-369.570	0.400
100	35	-365.487	-365.901	0.414
100	36	-360.579	-358.580	-1.999
100	37	-364.262	-365.912	1.650
100	38	-363.035	-362.254	-0.781
100	39	-370.397	-369.573	-0.824
100	41	-363.032	-362.233	-0.799
100	42	-356.896	-357.343	0.447
100	43	-361.805	-362.234	0.429
100	44	-365.488	-364.685	-0.803
	Max	-355.670	-357.172	7.550
	Average	-363.124	-364.202	1.079
	Min	-370.486	-373.124	-3.492
	Std Dev	4.102	4.161	2.048

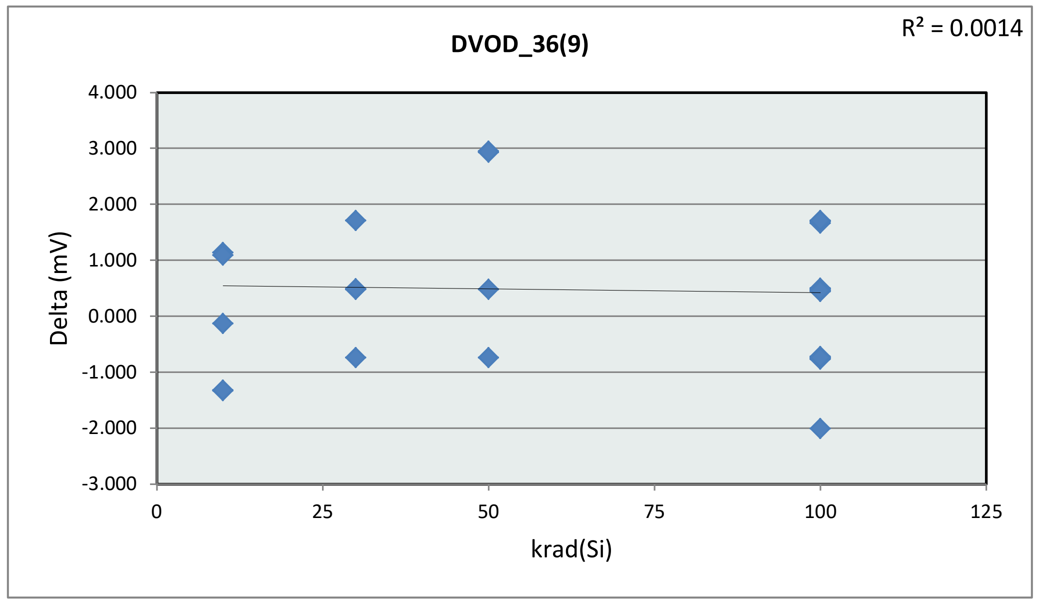


	VODL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-366.793	-373.124	-364.536	-372.020
Average	-364.838	-367.726	-361.098	-363.963
Max	-361.902	-360.855	-357.172	-357.343
UL	-320.000	-320.000	-320.000	-320.000

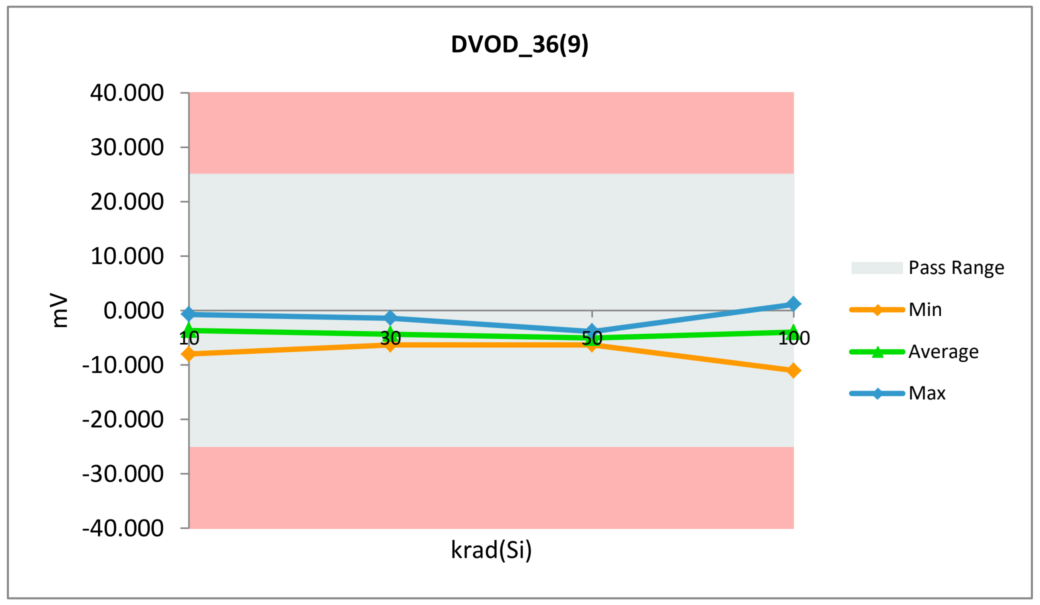


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-5.684	-5.551	-0.133
10	2	-3.232	-1.899	-1.333
10	3	-2.006	-0.684	-1.322
10	4	-0.780	-1.911	1.131
10	5	-6.912	-7.996	1.084
30	1	-2.126	-1.381	-0.745
30	2	-4.583	-6.293	1.710
30	3	-4.578	-5.060	0.482
30	4	-3.352	-3.834	0.482
30	5	-4.584	-5.067	0.483
50	11	-5.807	-5.065	-0.742
50	12	-3.346	-6.289	2.943
50	13	-0.896	-3.826	2.930
50	14	-3.355	-6.291	2.936
50	15	-3.353	-3.832	0.479
100	22	-5.686	-6.138	0.452
100	23	1.676	1.180	0.496
100	24	-2.007	-2.497	0.490
100	25	-8.141	-8.588	0.447
100	26	-0.777	-2.478	1.701
100	27	-8.140	-8.579	0.439
100	28	-5.689	-4.941	-0.748
100	29	-3.229	-2.458	-0.771
100	30	-3.234	-4.935	1.701
100	31	-3.233	-2.479	-0.754
100	32	-2.006	-3.706	1.700
100	33	-4.460	-6.149	1.689
100	34	-9.369	-11.030	1.661
100	35	0.451	-0.026	0.477
100	36	-3.233	-2.487	-0.746
100	37	-2.007	-3.714	1.707
100	38	-2.009	-1.283	-0.726
100	39	-4.461	-3.705	-0.756
100	41	-8.139	-6.129	-2.010
100	42	-3.229	-3.678	0.449
100	43	-2.003	-2.465	0.462
100	44	-2.005	-1.258	-0.747
	Max	1.676	1.180	2.943
	Average	-3.663	-4.122	0.459
	Min	-9.369	-11.030	-2.010
	Std Dev	2.454	2.595	1.246



	DVOD_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-7.996	-6.293	-6.291	-11.030
Average	-3.608	-4.327	-5.061	-3.979
Max	-0.684	-1.381	-3.826	1.180
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
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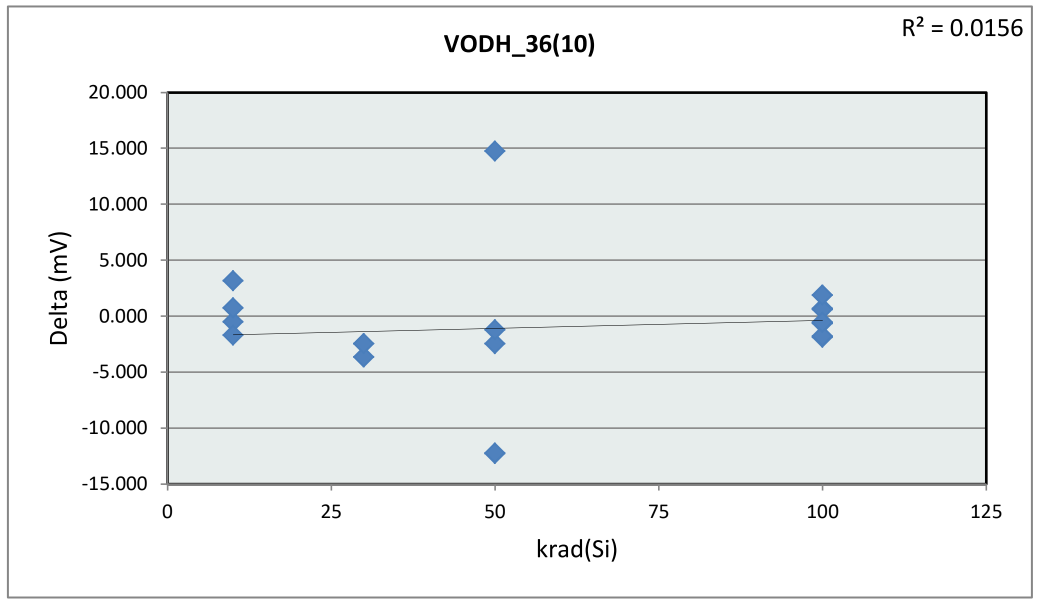
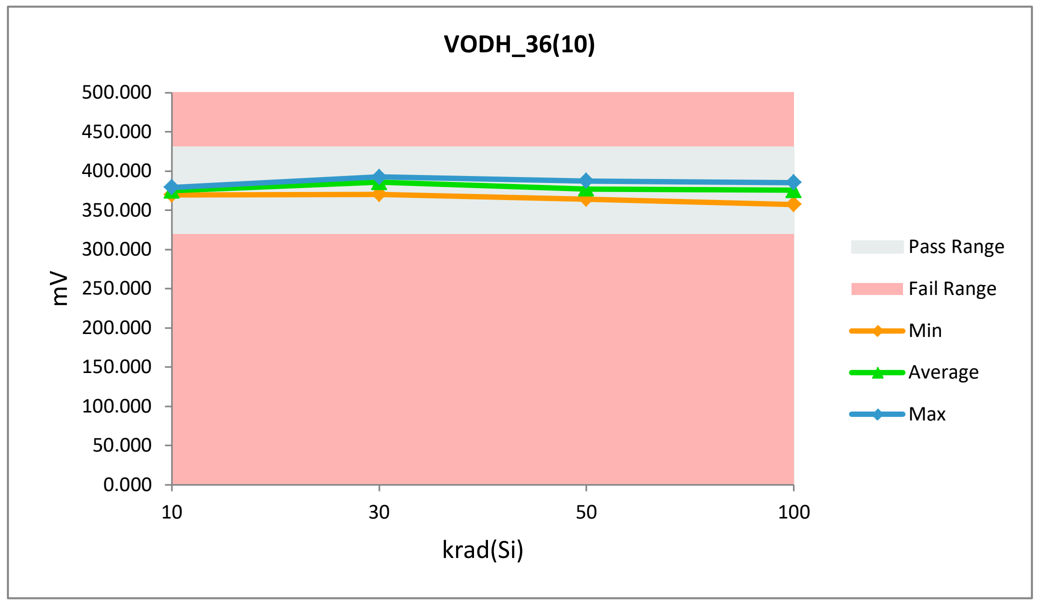
		VODH_36(10)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	375.079	375.595	-0.516
10	2	375.075	376.809	-1.734
10	3	379.985	379.255	0.730
10	4	370.162	369.461	0.701
10	5	375.079	371.926	3.153
30	1	384.950	387.402	-2.452
30	2	366.539	370.219	-3.680
30	3	386.177	388.629	-2.452
30	4	386.180	389.856	-3.676
30	5	389.859	392.311	-2.452
50	11	371.449	383.720	-12.271
50	12	387.407	372.674	14.733
50	13	375.134	387.402	-12.268
50	14	361.631	364.082	-2.451
50	15	376.367	377.583	-1.216
100	22	375.074	376.903	-1.829
100	23	362.799	363.452	-0.653
100	24	373.846	375.672	-1.826
100	25	379.980	379.332	0.648
100	26	373.846	374.453	-0.607
100	27	377.525	378.111	-0.586
100	28	375.072	373.226	1.846
100	29	377.527	375.674	1.853
100	30	381.214	381.799	-0.585
100	31	378.752	378.113	0.639
100	32	373.844	374.447	-0.603
100	33	355.437	357.342	-1.905
100	34	378.759	380.574	-1.815
100	35	386.110	385.421	0.689
100	36	373.850	373.245	0.605
100	37	372.622	372.016	0.606
100	38	360.347	359.792	0.555
100	39	383.658	384.210	-0.552
100	41	378.750	379.323	-0.573
100	42	373.845	372.005	1.840
100	43	378.757	379.347	-0.590
100	44	379.984	380.567	-0.583
	Max	389.859	392.311	14.733
	Average	376.018	376.809	-0.791
	Min	355.437	357.342	-12.271
	Std Dev	7.661	7.937	4.052



	VODH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	369.461	370.219	364.082	357.342
Average	374.609	385.683	377.092	375.228
Max	379.255	392.311	387.402	385.421
UL	430.000	430.000	430.000	430.000



HDR Biased TID Report
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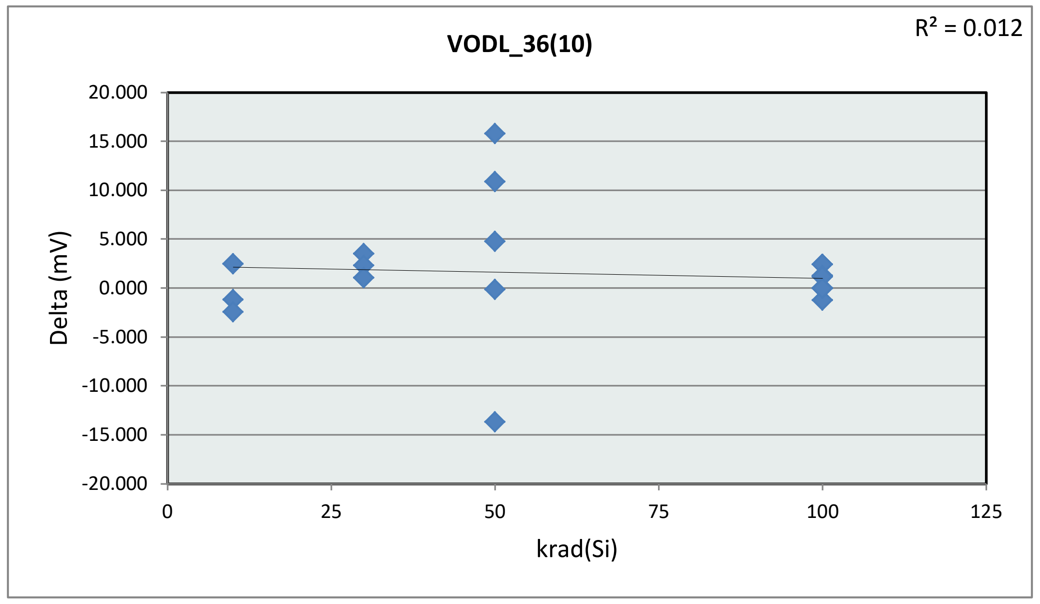
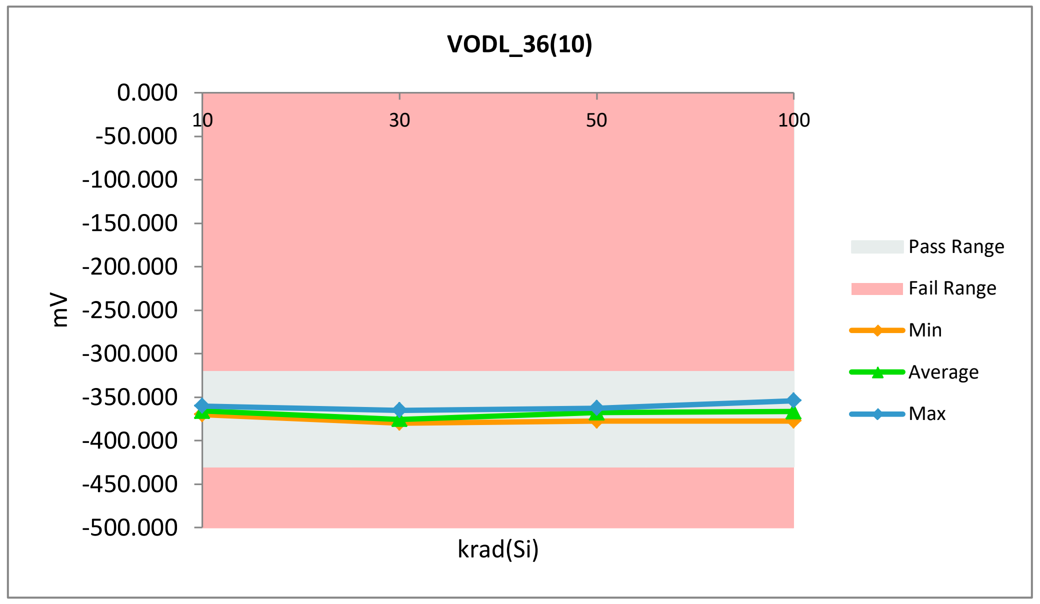
		VODL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-362.565	-365.040	2.475
10	2	-367.478	-369.938	2.460
10	3	-367.477	-369.935	2.458
10	4	-361.345	-360.176	-1.169
10	5	-366.247	-363.815	-2.432
30	1	-374.963	-378.467	3.504
30	2	-361.455	-364.966	3.511
30	3	-373.736	-376.012	2.276
30	4	-378.643	-379.694	1.051
30	5	-377.419	-378.467	1.048
50	11	-362.683	-373.558	10.875
50	12	-376.189	-362.511	-13.678
50	13	-361.453	-377.240	15.787
50	14	-357.769	-362.511	4.742
50	15	-362.676	-362.511	-0.165
100	22	-363.796	-366.208	2.412
100	23	-353.979	-353.993	0.014
100	24	-365.025	-367.437	2.412
100	25	-369.937	-369.889	-0.048
100	26	-363.797	-363.767	-0.030
100	27	-368.710	-369.889	1.179
100	28	-366.253	-368.664	2.411
100	29	-366.253	-366.216	-0.037
100	30	-367.476	-369.866	2.390
100	31	-368.711	-369.887	1.176
100	32	-365.026	-367.443	2.417
100	33	-352.751	-353.993	1.242
100	34	-366.249	-367.426	1.177
100	35	-376.081	-377.245	1.164
100	36	-365.020	-363.754	-1.266
100	37	-363.794	-363.760	-0.034
100	38	-353.977	-353.986	0.009
100	39	-374.850	-374.789	-0.061
100	41	-372.394	-373.566	1.172
100	42	-366.253	-364.996	-1.257
100	43	-369.932	-371.097	1.165
100	44	-367.478	-367.433	-0.045
	Max	-352.751	-353.986	15.787
	Average	-366.482	-367.842	1.360
	Min	-378.643	-379.694	-13.678
	Std Dev	6.342	6.617	4.110

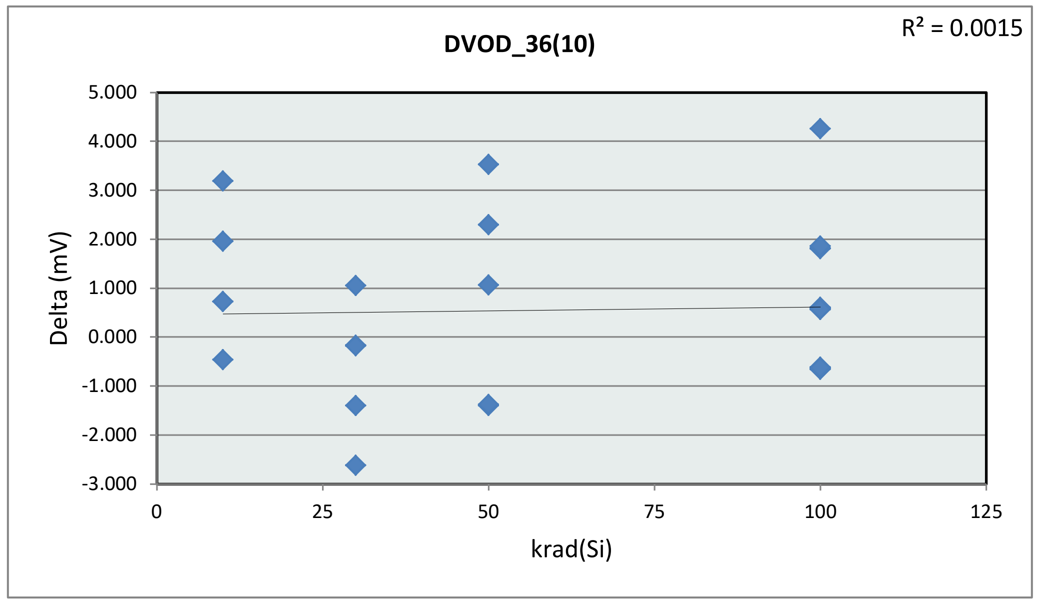


	VODL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-369.938	-379.694	-377.240	-377.245
Average	-365.781	-375.521	-367.666	-366.605
Max	-360.176	-364.966	-362.511	-353.986
UL	-320.000	-320.000	-320.000	-320.000

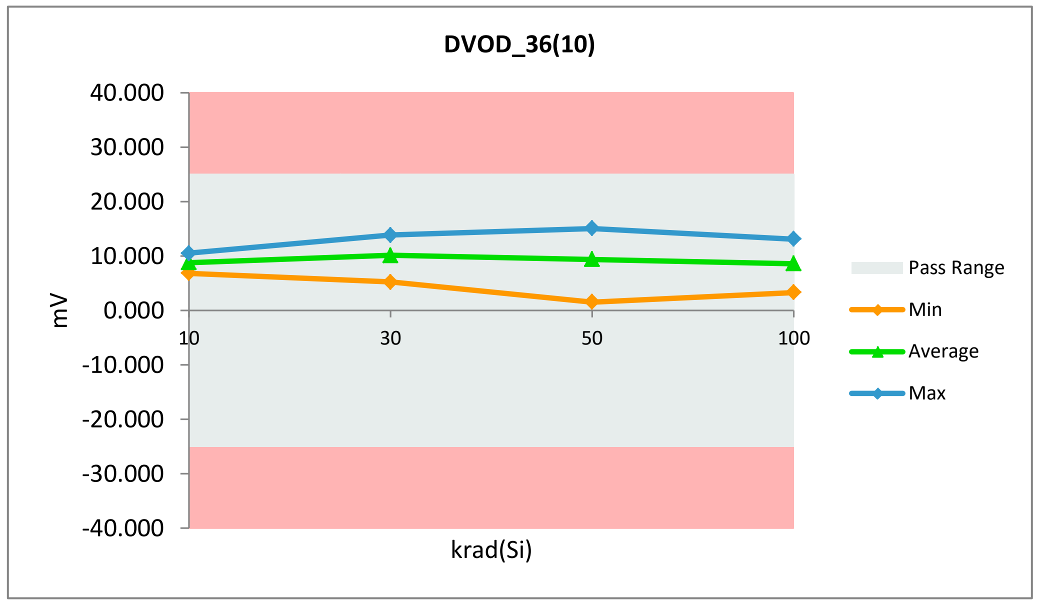


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	12.513	10.555	1.958
10	2	7.597	6.871	0.726
10	3	12.508	9.321	3.187
10	4	8.817	9.285	-0.468
10	5	8.832	8.111	0.721
30	1	9.987	8.935	1.052
30	2	5.085	5.253	-0.168
30	3	12.441	12.617	-0.176
30	4	7.537	10.162	-2.625
30	5	12.440	13.844	-1.404
50	11	8.765	10.162	-1.397
50	12	11.218	10.162	1.056
50	13	13.681	10.162	3.519
50	14	3.862	1.571	2.291
50	15	13.691	15.072	-1.381
100	22	11.278	10.695	0.583
100	23	8.820	9.458	-0.638
100	24	8.821	8.235	0.586
100	25	10.043	9.443	0.600
100	26	10.049	10.685	-0.636
100	27	8.816	8.222	0.594
100	28	8.818	4.562	4.256
100	29	11.274	9.458	1.816
100	30	13.738	11.933	1.805
100	31	10.041	8.226	1.815
100	32	8.818	7.004	1.814
100	33	2.686	3.348	-0.662
100	34	12.509	13.149	-0.640
100	35	10.029	8.176	1.853
100	36	8.830	9.490	-0.660
100	37	8.828	8.256	0.572
100	38	6.370	5.806	0.564
100	39	8.808	9.420	-0.612
100	41	6.356	5.756	0.600
100	42	7.592	7.008	0.584
100	43	8.825	8.250	0.575
100	44	12.506	13.134	-0.628
	Max	13.738	15.072	4.256
	Average	9.536	8.967	0.568
	Min	2.686	1.571	-2.625
	Std Dev	2.642	2.836	1.458

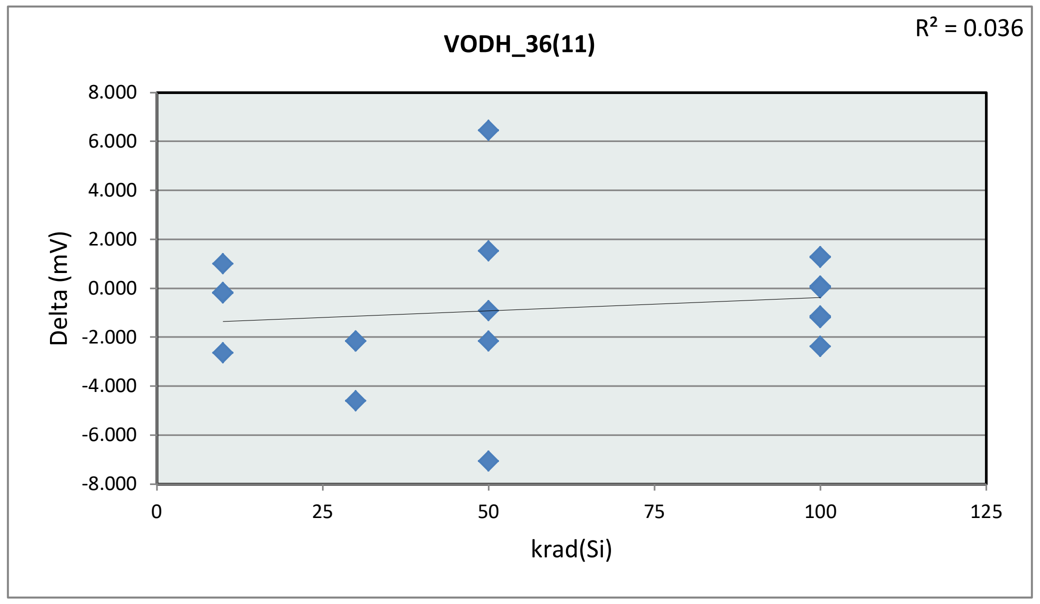


	DVOD_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	6.871	5.253	1.571	3.348
Average	8.829	10.162	9.426	8.623
Max	10.555	13.844	15.072	13.149
UL	25.000	25.000	25.000	25.000

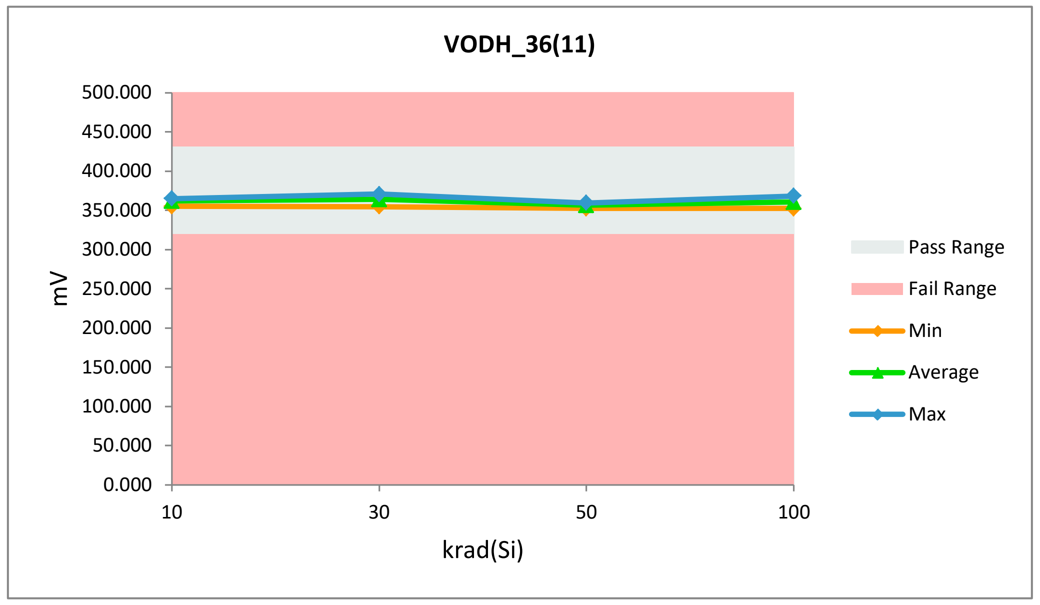


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	361.029	361.233	-0.204
10	2	362.255	364.892	-2.637
10	3	364.709	364.889	-0.180
10	4	362.254	362.442	-0.188
10	5	356.120	355.125	0.995
30	1	364.677	366.834	-2.157
30	2	352.403	354.561	-2.158
30	3	358.541	360.699	-2.158
30	4	365.905	370.516	-4.611
30	5	364.675	366.831	-2.156
50	11	352.404	359.469	-7.065
50	12	358.544	352.108	6.436
50	13	356.087	358.248	-2.161
50	14	354.857	355.789	-0.932
50	15	358.541	357.018	1.523
100	22	358.574	359.761	-1.187
100	23	357.346	358.533	-1.187
100	24	363.481	365.858	-2.377
100	25	358.573	358.537	0.036
100	26	359.801	358.537	1.264
100	27	356.120	356.097	0.023
100	28	358.572	359.749	-1.177
100	29	358.575	358.547	0.028
100	30	367.163	368.303	-1.140
100	31	365.937	365.867	0.070
100	32	362.255	360.978	1.277
100	33	351.210	352.425	-1.215
100	34	361.028	359.759	1.269
100	35	365.938	365.871	0.067
100	36	357.345	357.310	0.035
100	37	361.027	363.417	-2.390
100	38	362.253	360.968	1.285
100	39	365.936	365.864	0.072
100	41	356.120	356.101	0.019
100	42	353.666	354.883	-1.217
100	43	361.029	360.987	0.042
100	44	363.482	364.645	-1.163
	Max	367.163	370.516	6.436
	Average	359.958	360.639	-0.682
	Min	351.210	352.108	-7.065
	Std Dev	4.265	4.603	2.092

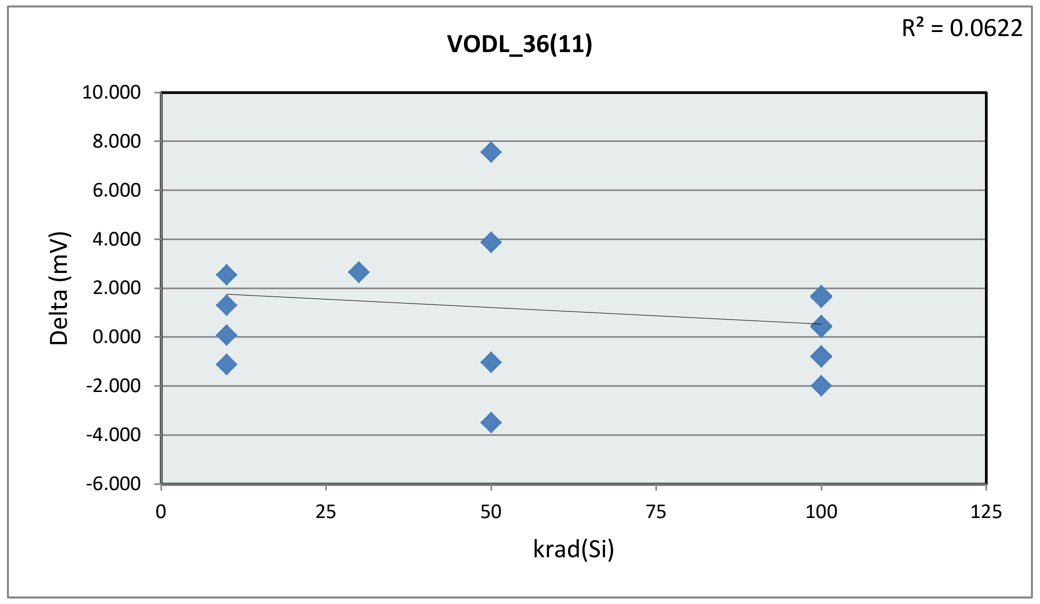


	VODH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	355.125	354.561	352.108	352.425
Average	361.716	363.888	356.526	360.591
Max	364.892	370.516	359.469	368.303
UL	430.000	430.000	430.000	430.000

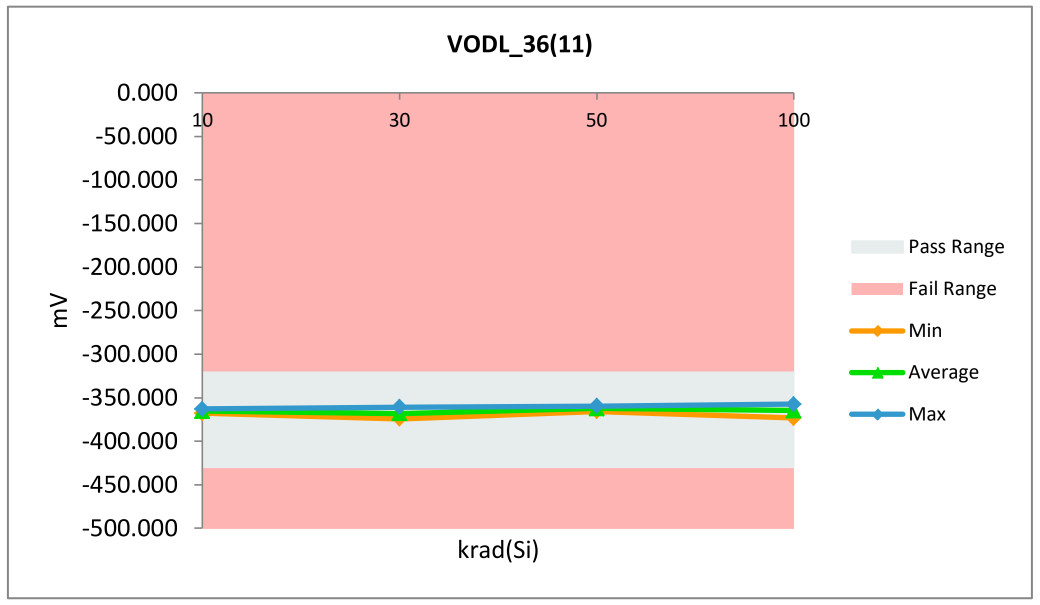


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-365.487	-366.789	1.302
10	2	-365.488	-368.017	2.529
10	3	-366.716	-366.798	0.082
10	4	-364.262	-363.137	-1.125
10	5	-364.260	-363.126	-1.134
30	1	-366.806	-369.444	2.638
30	2	-358.215	-360.857	2.642
30	3	-361.895	-364.535	2.640
30	4	-371.714	-374.353	2.639
30	5	-369.262	-371.901	2.639
50	11	-358.214	-365.765	7.551
50	12	-363.120	-359.627	-3.493
50	13	-359.440	-363.304	3.864
50	14	-358.216	-362.082	3.866
50	15	-361.896	-360.853	-1.043
100	22	-363.034	-364.685	1.651
100	23	-356.898	-358.582	1.684
100	24	-366.717	-368.362	1.645
100	25	-366.716	-365.909	-0.807
100	26	-361.807	-362.244	0.437
100	27	-363.033	-364.683	1.650
100	28	-365.490	-367.139	1.649
100	29	-361.805	-362.234	0.429
100	30	-371.625	-373.246	1.621
100	31	-367.943	-368.353	0.410
100	32	-363.034	-363.468	0.434
100	33	-356.898	-357.360	0.462
100	34	-369.170	-370.796	1.626
100	35	-366.715	-367.126	0.411
100	36	-361.807	-359.805	-2.002
100	37	-365.489	-365.916	0.427
100	38	-364.263	-363.479	-0.784
100	39	-370.398	-369.576	-0.822
100	41	-364.260	-363.458	-0.802
100	42	-358.124	-358.568	0.444
100	43	-363.033	-362.237	-0.796
100	44	-366.716	-365.910	-0.806
	Max	-356.898	-357.360	7.551
	Average	-364.053	-364.966	0.912
	Min	-371.714	-374.353	-3.493
	Std Dev	3.968	4.108	1.995

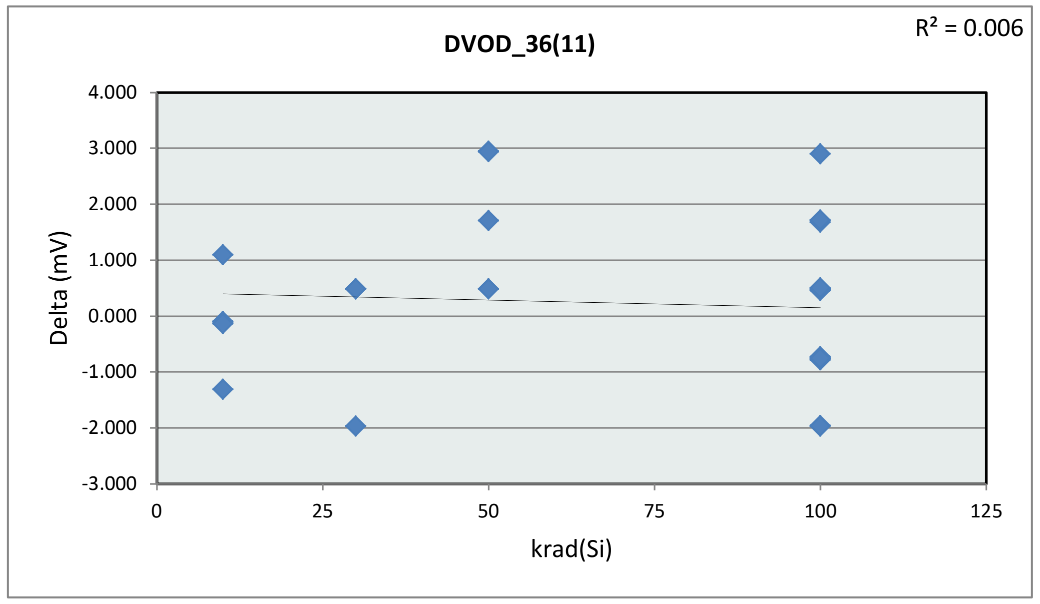


	VODL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-368.017	-374.353	-365.765	-373.246
Average	-365.573	-368.218	-362.326	-364.688
Max	-363.126	-360.857	-359.627	-357.360
UL	-320.000	-320.000	-320.000	-320.000

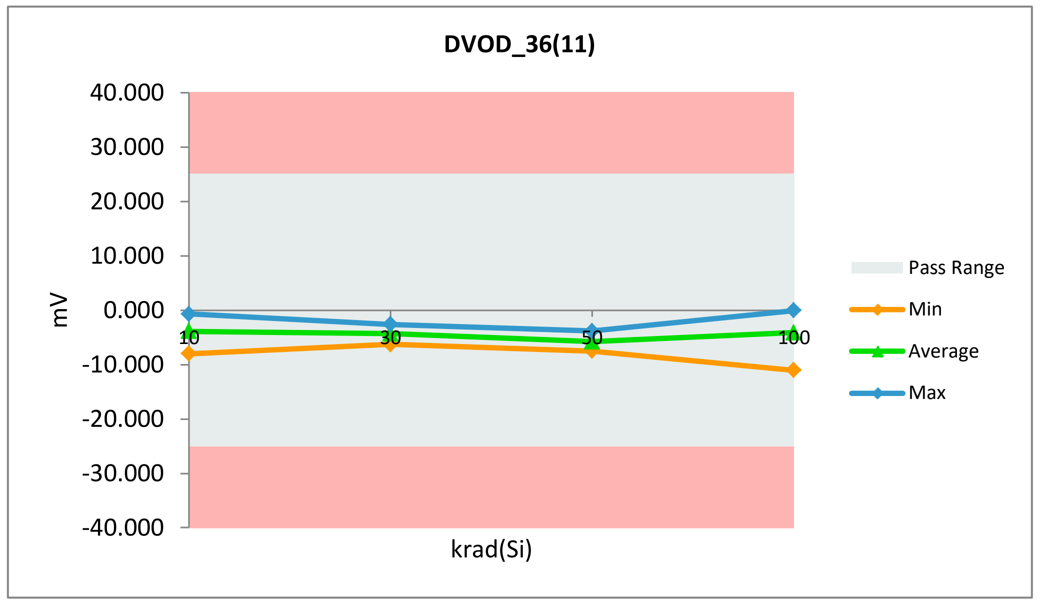


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-4.458	-5.556	1.098
10	2	-3.233	-3.125	-0.108
10	3	-2.007	-1.909	-0.098
10	4	-2.008	-0.694	-1.314
10	5	-8.140	-8.001	-0.139
30	1	-2.128	-2.611	0.483
30	2	-5.812	-6.296	0.484
30	3	-3.354	-3.836	0.482
30	4	-5.809	-3.837	-1.972
30	5	-4.587	-5.070	0.483
50	11	-5.810	-6.295	0.485
50	12	-4.575	-7.519	2.944
50	13	-3.353	-5.056	1.703
50	14	-3.358	-6.293	2.935
50	15	-3.355	-3.835	0.480
100	22	-4.460	-4.924	0.464
100	23	0.447	-0.049	0.496
100	24	-3.236	-2.504	-0.732
100	25	-8.142	-7.372	-0.770
100	26	-2.006	-3.707	1.701
100	27	-6.914	-8.586	1.672
100	28	-6.918	-7.390	0.472
100	29	-3.230	-3.687	0.457
100	30	-4.462	-4.942	0.480
100	31	-2.006	-2.486	0.480
100	32	-0.780	-2.491	1.711
100	33	-5.689	-4.935	-0.754
100	34	-8.142	-11.037	2.895
100	35	-0.777	-1.255	0.478
100	36	-4.462	-2.495	-1.967
100	37	-4.462	-2.499	-1.963
100	38	-2.010	-2.512	0.502
100	39	-4.462	-3.712	-0.750
100	41	-8.140	-7.357	-0.783
100	42	-4.458	-3.686	-0.772
100	43	-2.004	-1.250	-0.754
100	44	-3.233	-1.265	-1.968
	Max	0.447	-0.049	2.944
	Average	-4.095	-4.326	0.231
	Min	-8.142	-11.037	-1.972
	Std Dev	2.186	2.485	1.301

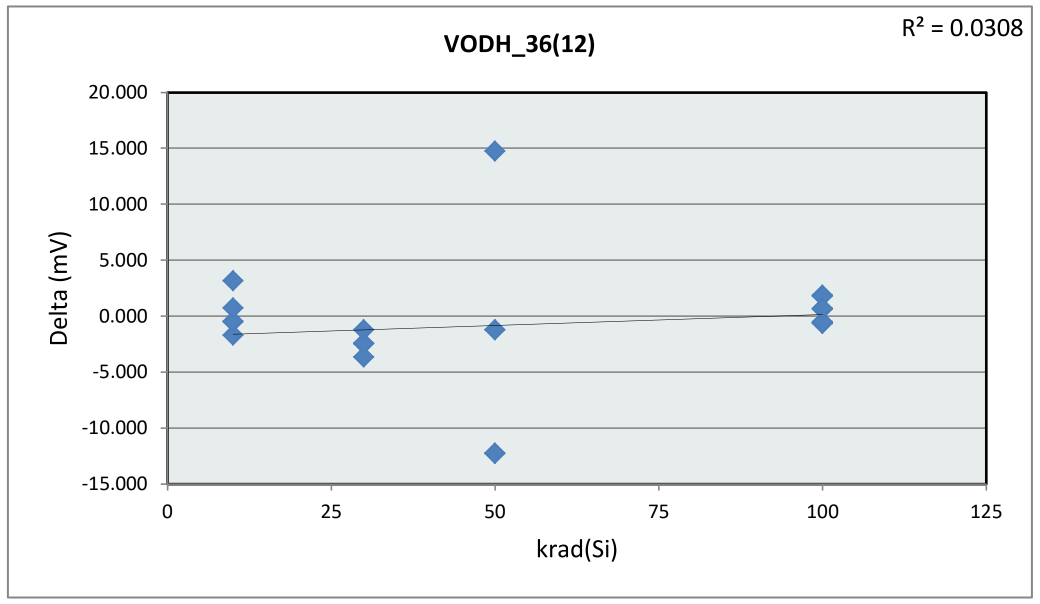


	DVOD_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-8.001	-6.296	-7.519	-11.037
Average	-3.857	-4.330	-5.800	-4.097
Max	-0.694	-2.611	-3.835	-0.049
UL	25.000	25.000	25.000	25.000

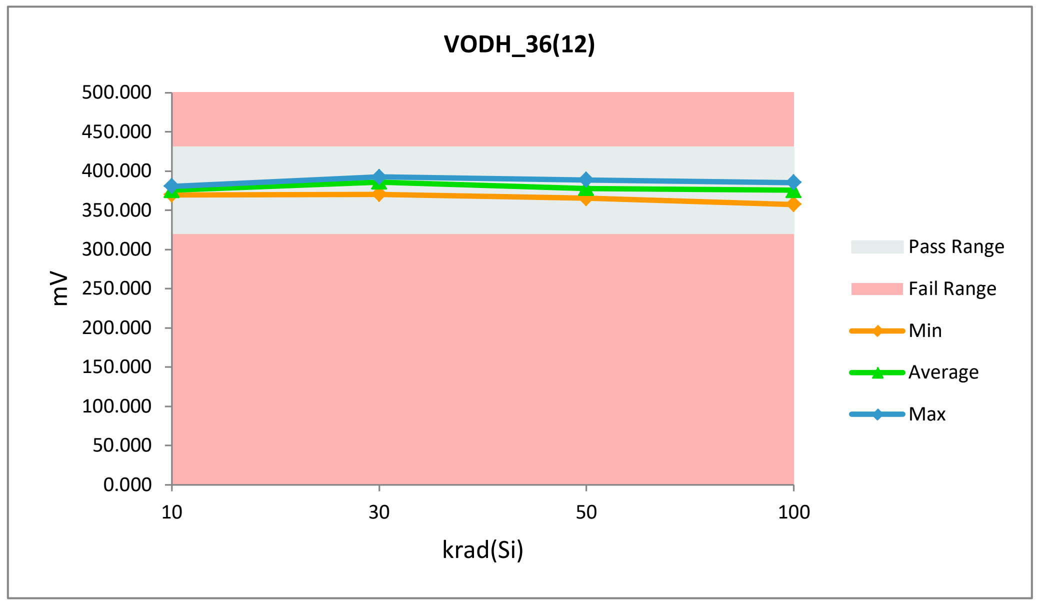


HDR Biased TID Report
SN55LVCP22A-SP

		VODH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	375.077	375.588	-0.511
10	2	376.300	378.023	-1.723
10	3	379.983	380.471	-0.488
10	4	370.160	369.456	0.704
10	5	376.304	373.140	3.164
30	1	384.948	387.402	-2.454
30	2	367.766	370.219	-2.453
30	3	386.176	389.856	-3.680
30	4	387.406	389.856	-2.450
30	5	391.086	392.311	-1.225
50	11	372.675	384.947	-12.272
50	12	387.405	372.674	14.731
50	13	376.361	388.629	-12.268
50	14	364.084	365.309	-1.225
50	15	376.365	377.583	-1.218
100	22	376.300	376.895	-0.595
100	23	364.024	364.665	-0.641
100	24	376.298	375.666	0.632
100	25	381.205	380.548	0.657
100	26	375.071	374.447	0.624
100	27	377.524	378.103	-0.579
100	28	375.069	374.441	0.628
100	29	377.525	375.668	1.857
100	30	381.212	381.794	-0.582
100	31	378.750	379.330	-0.580
100	32	375.069	375.661	-0.592
100	33	356.662	357.334	-0.672
100	34	381.211	380.567	0.644
100	35	384.881	385.416	-0.535
100	36	375.075	373.239	1.836
100	37	373.847	372.010	1.837
100	38	361.572	359.786	1.786
100	39	384.884	384.204	0.680
100	41	379.975	379.317	0.658
100	42	372.616	371.999	0.617
100	43	379.983	380.563	-0.580
100	44	381.210	380.561	0.649
	Max	391.086	392.311	14.731
	Average	376.812	377.235	-0.422
	Min	356.662	357.334	-12.272
	Std Dev	7.406	7.966	4.020

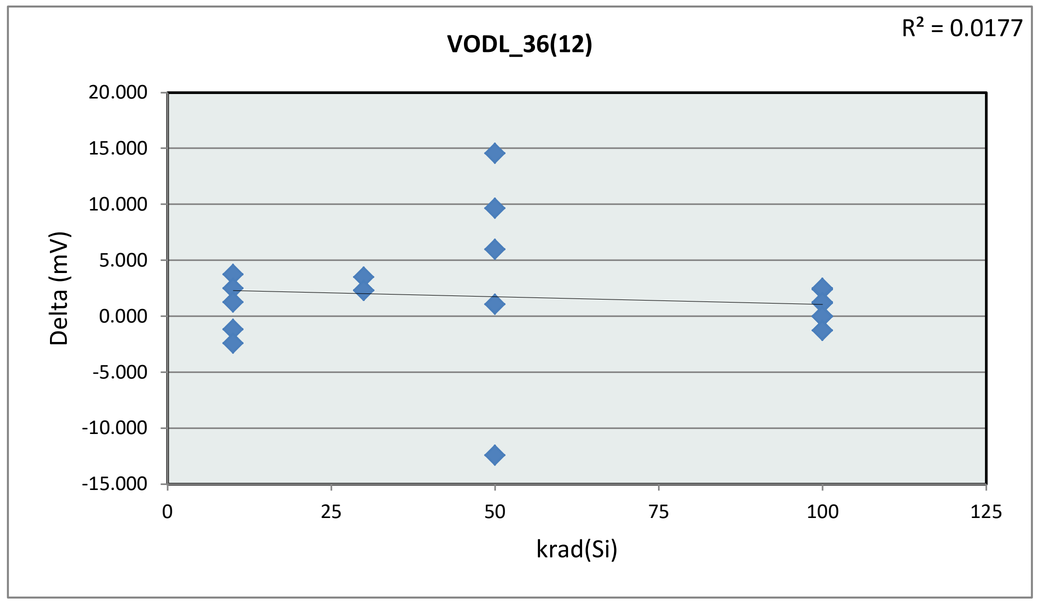


	VODH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	369.456	370.219	365.309	357.334
Average	375.336	385.929	377.828	375.555
Max	380.471	392.311	388.629	385.416
UL	430.000	430.000	430.000	430.000

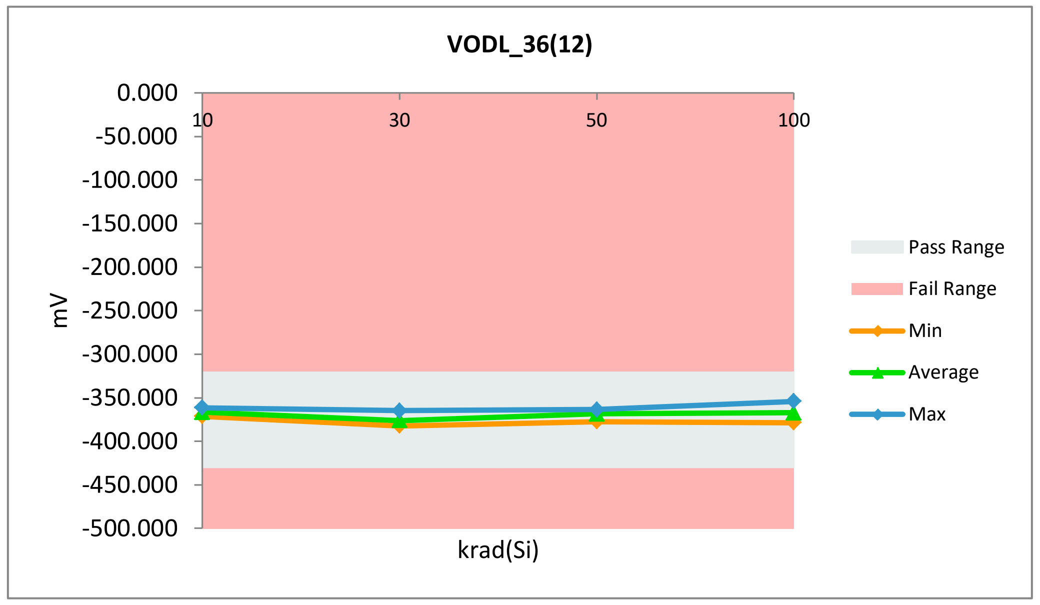


HDR Biased TID Report
SN55LVCP22A-SP

		VODL_36(12)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-362.567	-366.269	3.702
10	2	-368.707	-371.167	2.460
10	3	-368.706	-369.942	1.236
10	4	-362.575	-361.403	-1.172
10	5	-367.476	-365.044	-2.432
30	1	-376.192	-378.467	2.275
30	2	-362.684	-364.966	2.282
30	3	-373.737	-376.012	2.275
30	4	-378.645	-382.149	3.504
30	5	-377.421	-379.694	2.273
50	11	-365.140	-374.785	9.645
50	12	-376.190	-363.739	-12.451
50	13	-362.683	-377.240	14.557
50	14	-357.771	-363.739	5.968
50	15	-362.677	-363.739	1.062
100	22	-365.026	-367.437	2.411
100	23	-353.982	-355.224	1.242
100	24	-367.482	-368.666	1.184
100	25	-371.167	-371.118	-0.049
100	26	-365.026	-364.996	-0.030
100	27	-368.711	-371.120	2.409
100	28	-368.711	-368.670	-0.041
100	29	-366.255	-366.221	-0.034
100	30	-368.705	-371.095	2.390
100	31	-368.713	-371.114	2.401
100	32	-366.256	-367.450	1.194
100	33	-352.753	-355.222	2.469
100	34	-367.478	-367.433	-0.045
100	35	-377.310	-378.474	1.164
100	36	-366.250	-364.983	-1.267
100	37	-363.796	-364.989	1.193
100	38	-353.979	-353.992	0.013
100	39	-374.852	-374.795	-0.057
100	41	-372.396	-373.572	1.176
100	42	-366.255	-367.446	1.191
100	43	-371.162	-371.105	-0.057
100	44	-368.708	-367.439	-1.269
	Max	-352.753	-353.992	14.557
	Average	-367.247	-368.673	1.426
	Min	-378.645	-382.149	-12.451
	Std Dev	6.358	6.559	3.820

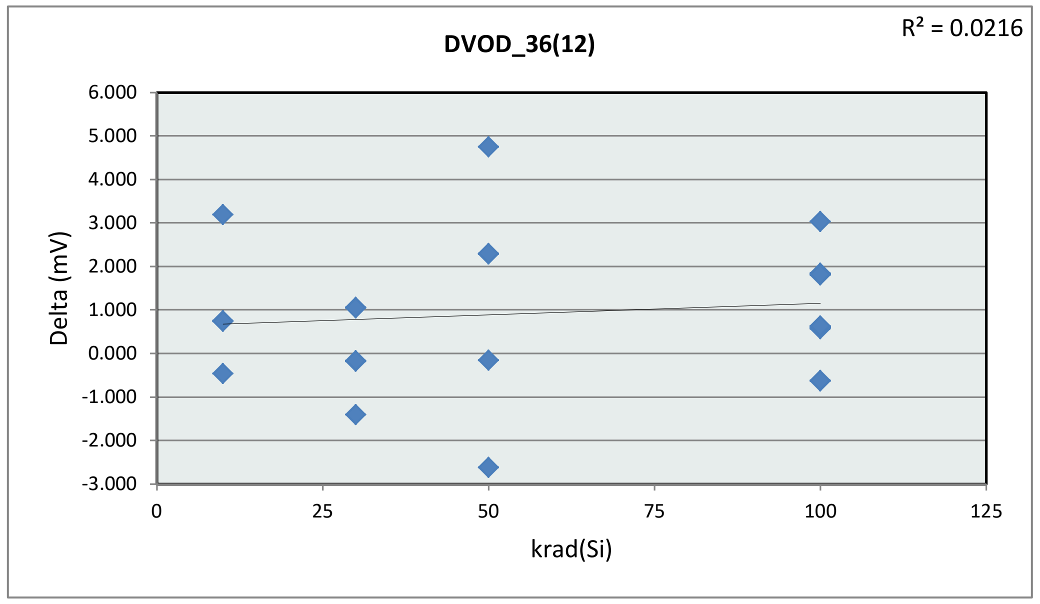


	VODL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-371.167	-382.149	-377.240	-378.474
Average	-366.765	-376.258	-368.648	-367.389
Max	-361.403	-364.966	-363.739	-353.992
UL	-320.000	-320.000	-320.000	-320.000

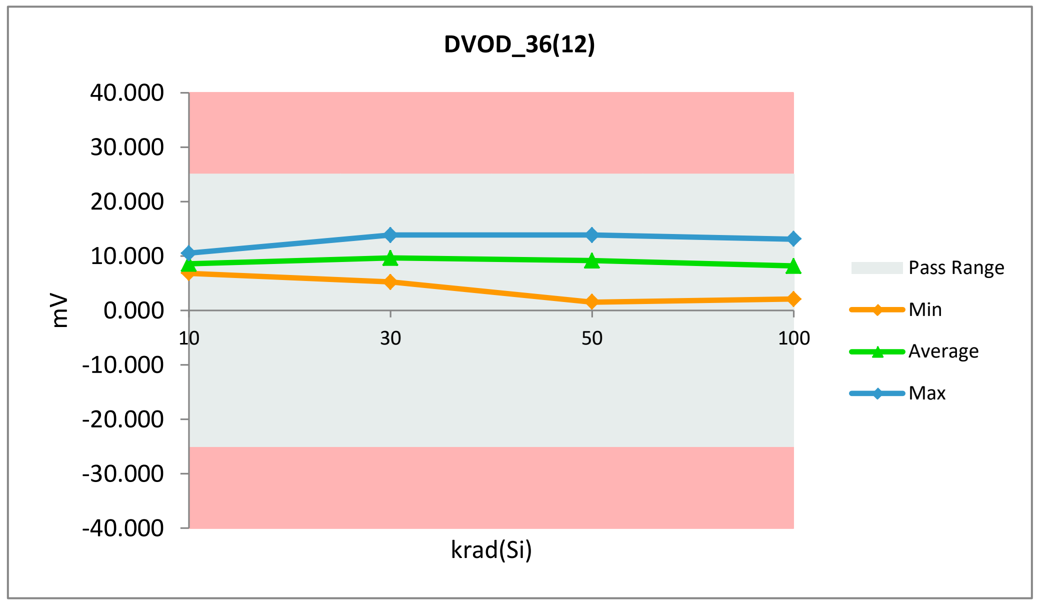


HDR Biased TID Report
SN55LVCP22A-SP

		DVOD_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	12.510	9.319	3.191
10	2	7.593	6.856	0.737
10	3	11.277	10.529	0.748
10	4	7.585	8.053	-0.468
10	5	8.827	8.096	0.731
30	1	8.756	8.935	-0.179
30	2	5.082	5.253	-0.171
30	3	12.439	13.844	-1.405
30	4	8.762	7.707	1.055
30	5	13.665	12.617	1.048
50	11	7.535	10.162	-2.627
50	12	11.215	8.935	2.280
50	13	13.678	11.389	2.289
50	14	6.314	1.571	4.743
50	15	13.688	13.844	-0.156
100	22	11.274	9.458	1.816
100	23	10.042	9.441	0.601
100	24	8.816	7.001	1.815
100	25	10.039	9.430	0.609
100	26	10.045	9.451	0.594
100	27	8.812	6.983	1.829
100	28	6.359	5.772	0.587
100	29	11.270	9.447	1.823
100	30	12.507	10.699	1.808
100	31	10.037	8.216	1.821
100	32	8.813	8.210	0.603
100	33	3.909	2.112	1.797
100	34	13.733	13.134	0.599
100	35	7.570	6.942	0.628
100	36	8.826	8.256	0.570
100	37	10.051	7.021	3.030
100	38	7.592	5.794	1.798
100	39	10.032	9.409	0.623
100	41	7.579	5.745	1.834
100	42	6.361	4.552	1.809
100	43	8.821	9.458	-0.637
100	44	12.502	13.122	-0.620
	Max	13.733	13.844	4.743
	Average	9.565	8.561	1.004
	Min	3.909	1.571	-2.627
	Std Dev	2.510	2.860	1.344



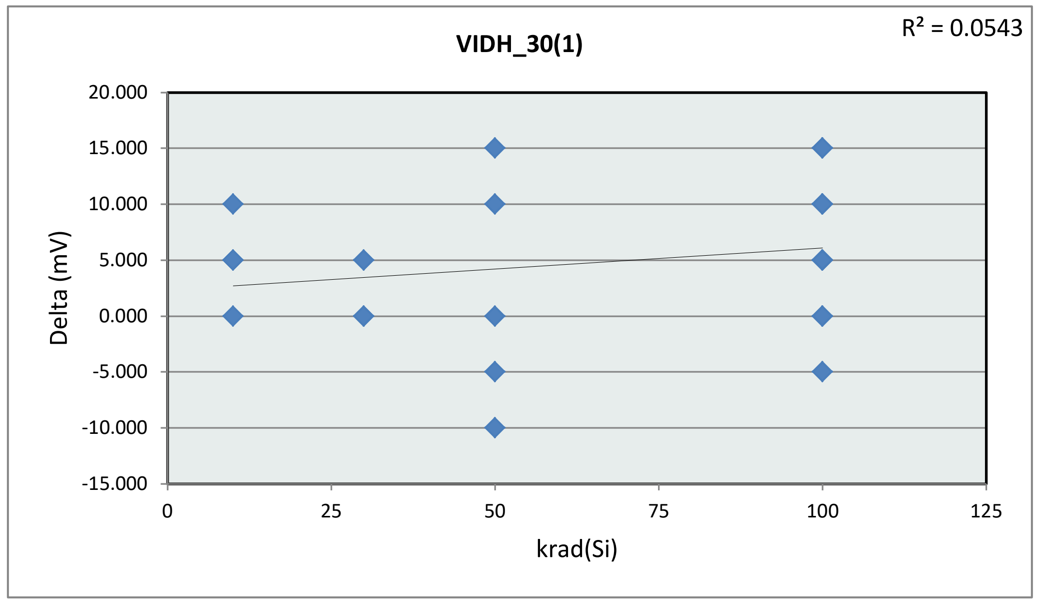
	DVOD_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	6.856	5.253	1.571	2.112
Average	8.571	9.671	9.180	8.166
Max	10.529	13.844	13.844	13.134
UL	25.000	25.000	25.000	25.000



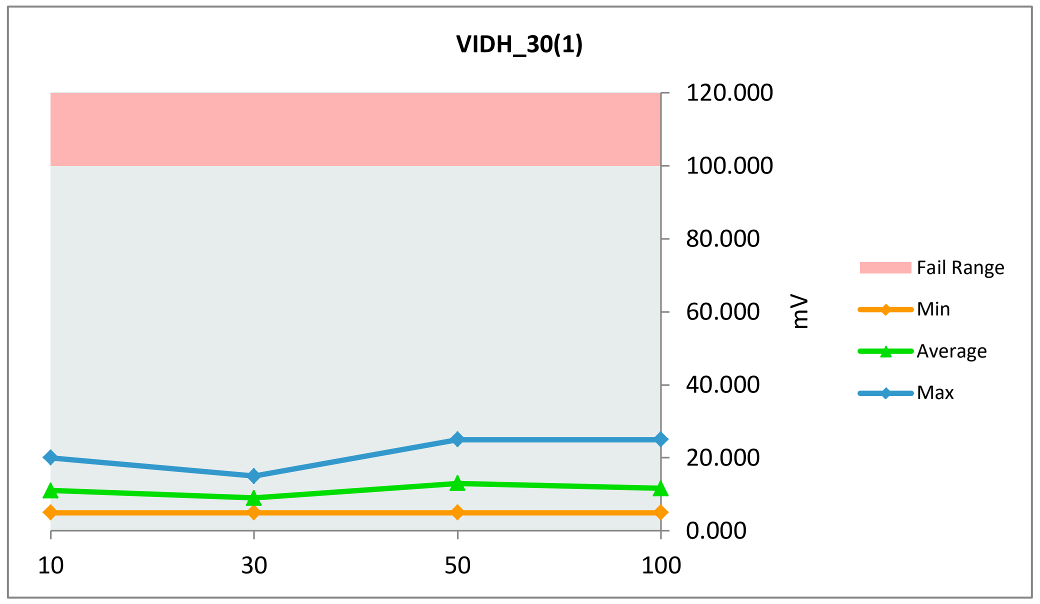
HDR Biased TID Report
SN55LVCP22A-SP

	VIDH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	25.000	20.000	5.000
10	2	5.000	5.000	0.000
10	3	15.000	10.000	5.000
10	4	15.000	10.000	5.000
10	5	20.000	10.000	10.000
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	10.000	5.000	5.000
30	4	20.000	15.000	5.000
30	5	15.000	15.000	0.000
50	11	20.000	5.000	15.000
50	12	10.000	20.000	-10.000
50	13	20.000	10.000	10.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	25.000	15.000	10.000
100	24	20.000	10.000	10.000
100	25	30.000	25.000	5.000
100	26	30.000	15.000	15.000
100	27	20.000	10.000	10.000
100	28	5.000	5.000	0.000
100	29	15.000	10.000	5.000
100	30	25.000	10.000	15.000
100	31	5.000	5.000	0.000
100	32	20.000	15.000	5.000
100	33	25.000	15.000	10.000
100	34	30.000	15.000	15.000
100	35	15.000	10.000	5.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	20.000	15.000	5.000
100	39	15.000	10.000	5.000
100	41	25.000	15.000	10.000
100	42	15.000	10.000	5.000
100	43	5.000	10.000	-5.000
100	44	20.000	15.000	5.000
	Max	30.000	25.000	15.000
	Average	16.351	11.351	5.000
	Min	5.000	5.000	-10.000
	Std Dev	8.049	5.483	5.893

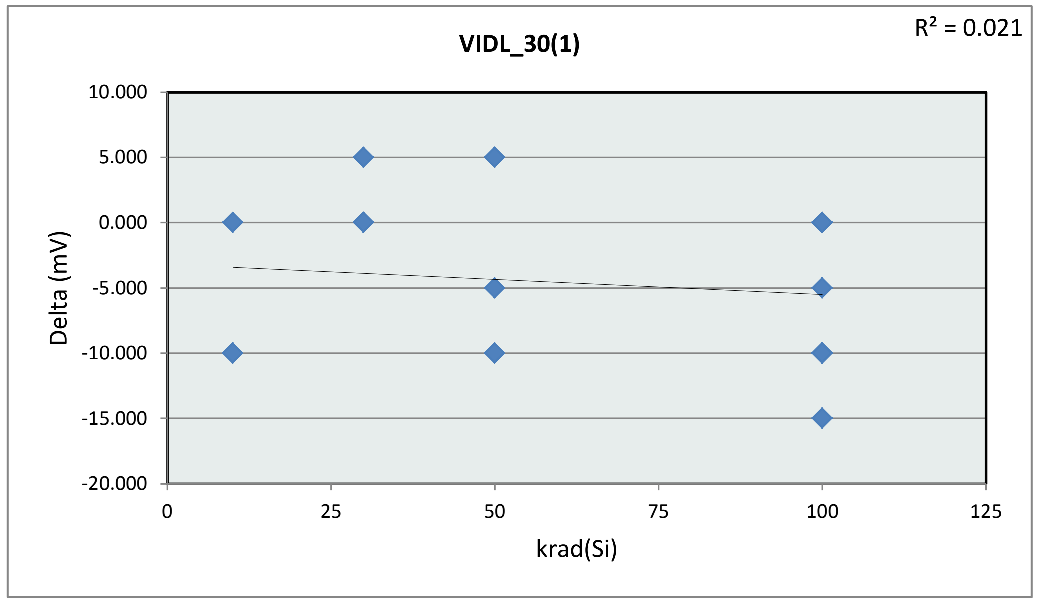


	VIDH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	11.000	9.000	13.000	11.591
Max	20.000	15.000	25.000	25.000
UL	100.000	100.000	100.000	100.000

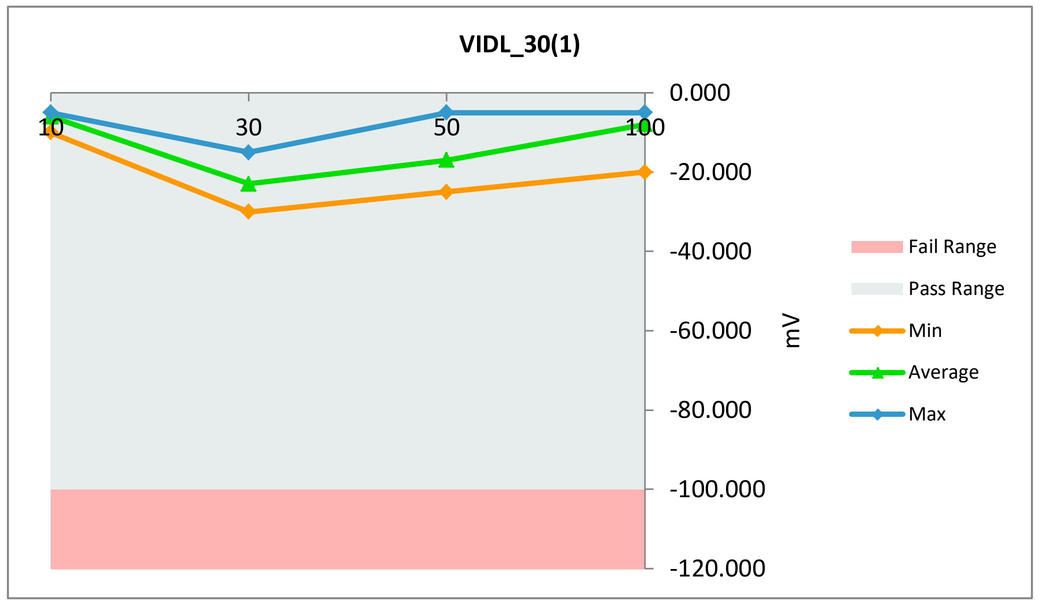


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-15.000	-5.000	-10.000
10	2	-20.000	-10.000	-10.000
10	3	-15.000	-5.000	-10.000
10	4	-15.000	-5.000	-10.000
10	5	-5.000	-5.000	0.000
30	1	-25.000	-25.000	0.000
30	2	-15.000	-15.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-15.000	-20.000	5.000
30	5	-25.000	-25.000	0.000
50	11	-15.000	-20.000	5.000
50	12	-25.000	-15.000	-10.000
50	13	-20.000	-25.000	5.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-15.000	-5.000	-10.000
100	23	-10.000	-5.000	-5.000
100	24	-5.000	-5.000	0.000
100	25	-20.000	-10.000	-10.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-20.000	-10.000
100	28	-30.000	-20.000	-10.000
100	29	-15.000	-5.000	-10.000
100	30	-5.000	-5.000	0.000
100	31	-25.000	-10.000	-15.000
100	32	-15.000	-5.000	-10.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-10.000	-10.000
100	36	-25.000	-15.000	-10.000
100	37	-25.000	-10.000	-15.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	41	-15.000	-5.000	-10.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-10.000	-5.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-15.811	-10.946	-4.865
	Min	-30.000	-30.000	-15.000
	Std Dev	8.540	7.623	5.832

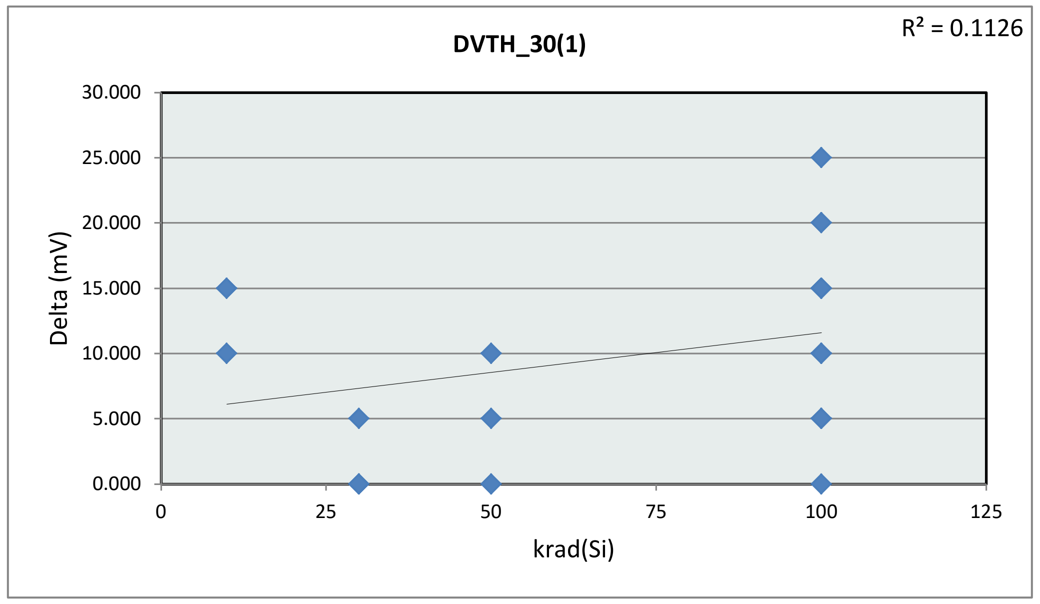


	VIDL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-10.000	-30.000	-25.000	-20.000
Average	-6.000	-23.000	-17.000	-7.955
Max	-5.000	-15.000	-5.000	-5.000
UL				

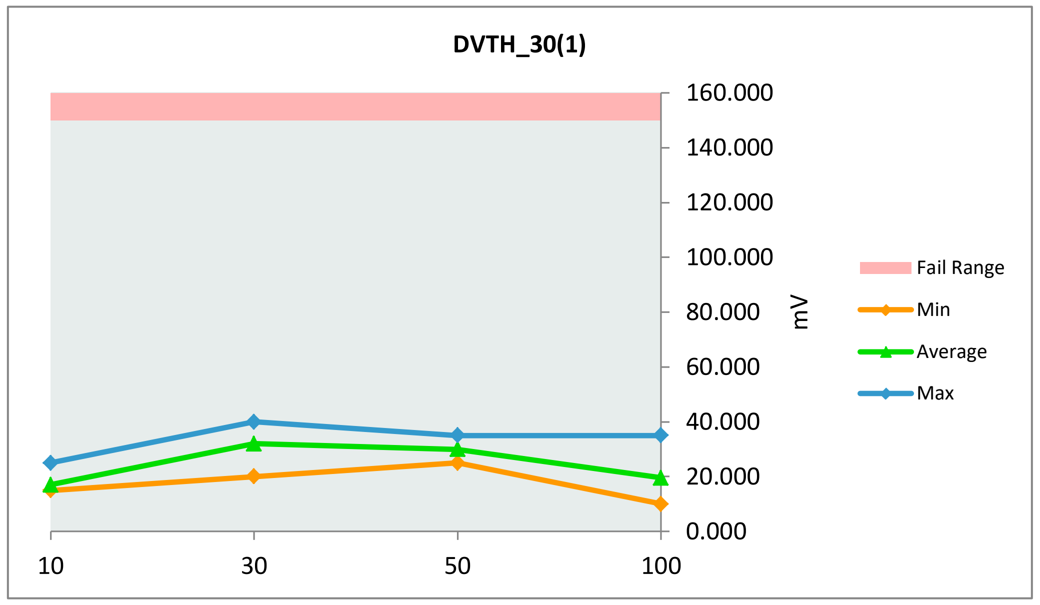


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	40.000	25.000	15.000
10	2	25.000	15.000	10.000
10	3	30.000	15.000	15.000
10	4	30.000	15.000	15.000
10	5	25.000	15.000	10.000
30	1	30.000	30.000	0.000
30	2	20.000	20.000	0.000
30	3	40.000	35.000	5.000
30	4	35.000	35.000	0.000
30	5	40.000	40.000	0.000
50	11	35.000	25.000	10.000
50	12	35.000	35.000	0.000
50	13	40.000	35.000	5.000
50	14	30.000	30.000	0.000
50	15	35.000	25.000	10.000
100	22	20.000	10.000	10.000
100	23	35.000	20.000	15.000
100	24	25.000	15.000	10.000
100	25	50.000	35.000	15.000
100	26	35.000	20.000	15.000
100	27	50.000	30.000	20.000
100	28	35.000	25.000	10.000
100	29	30.000	15.000	15.000
100	30	30.000	15.000	15.000
100	31	30.000	15.000	15.000
100	32	35.000	20.000	15.000
100	33	30.000	20.000	10.000
100	34	35.000	20.000	15.000
100	35	35.000	20.000	15.000
100	36	30.000	20.000	10.000
100	37	45.000	20.000	25.000
100	38	25.000	20.000	5.000
100	39	20.000	15.000	5.000
100	41	40.000	20.000	20.000
100	42	20.000	15.000	5.000
100	43	20.000	20.000	0.000
100	44	25.000	20.000	5.000
	Max	50.000	40.000	25.000
	Average	32.162	22.297	9.865
	Min	20.000	10.000	0.000
	Std Dev	7.865	7.601	6.613



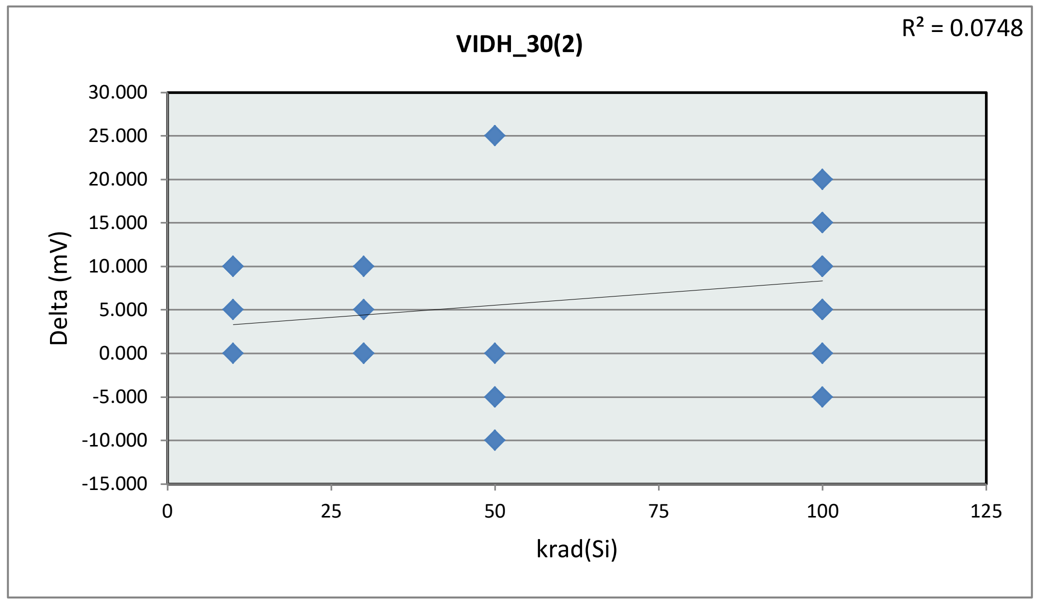
	DVTH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	20.000	25.000	10.000
Average	17.000	32.000	30.000	19.545
Max	25.000	40.000	35.000	35.000
UL	150.000	150.000	150.000	150.000



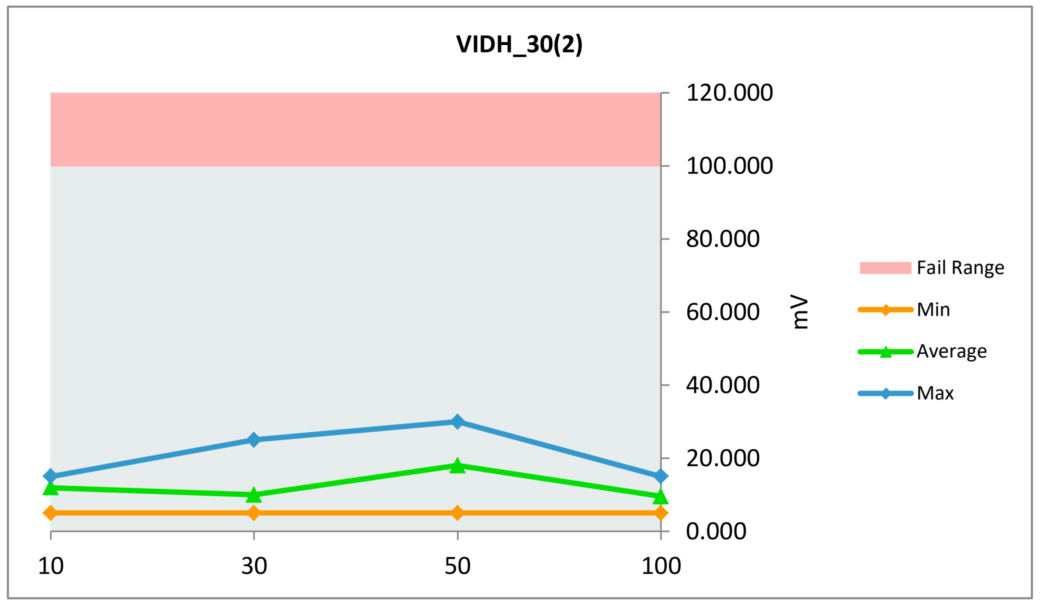
HDR Biased TID Report
SN55LVCP22A-SP

	VIDH_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	25.000	15.000	10.000
10	2	15.000	5.000	10.000
10	3	15.000	10.000	5.000
10	4	25.000	15.000	10.000
10	5	15.000	15.000	0.000
30	1	15.000	5.000	10.000
30	2	25.000	25.000	0.000
30	3	15.000	10.000	5.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	25.000	30.000	-5.000
50	13	15.000	25.000	-10.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	15.000	10.000	5.000
100	23	25.000	10.000	15.000
100	24	15.000	10.000	5.000
100	25	5.000	10.000	-5.000
100	26	20.000	10.000	10.000
100	27	30.000	10.000	20.000
100	28	15.000	5.000	10.000
100	29	20.000	15.000	5.000
100	30	20.000	10.000	10.000
100	31	20.000	10.000	10.000
100	32	25.000	10.000	15.000
100	33	25.000	15.000	10.000
100	34	20.000	10.000	10.000
100	35	25.000	10.000	15.000
100	36	10.000	5.000	5.000
100	37	25.000	10.000	15.000
100	38	15.000	5.000	10.000
100	39	20.000	10.000	10.000
100	41	5.000	5.000	0.000
100	42	20.000	10.000	10.000
100	43	15.000	5.000	10.000
100	44	15.000	15.000	0.000
	Max	30.000	30.000	25.000
	Average	17.838	11.081	6.757
	Min	5.000	5.000	-10.000
	Std Dev	7.026	6.361	7.380



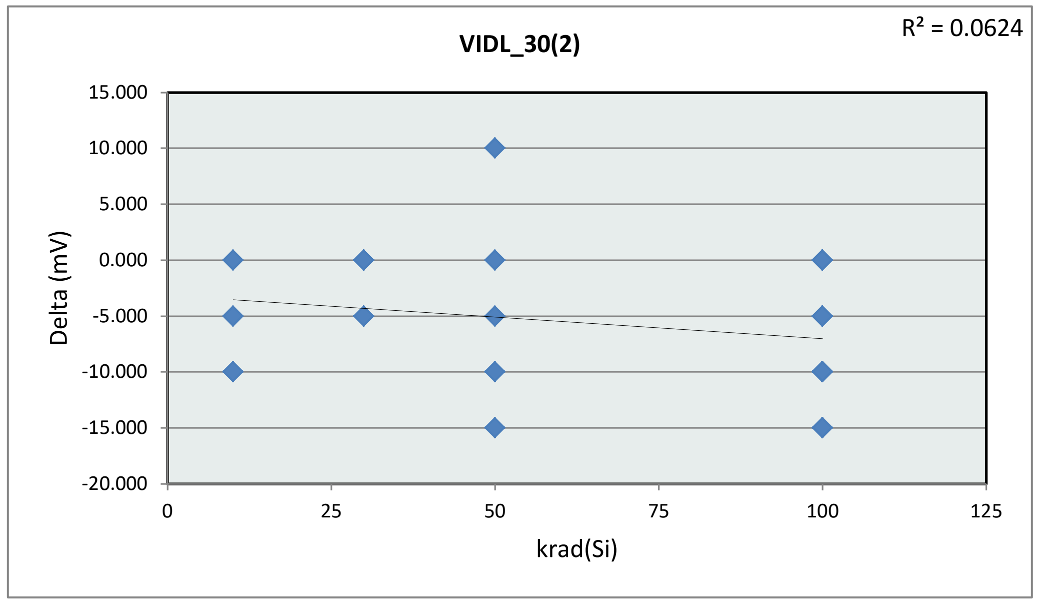
	VIDH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	12.000	10.000	18.000	9.545
Max	15.000	25.000	30.000	15.000
UL	100.000	100.000	100.000	100.000



HDR Biased TID Report
SN55LVCP22A-SP

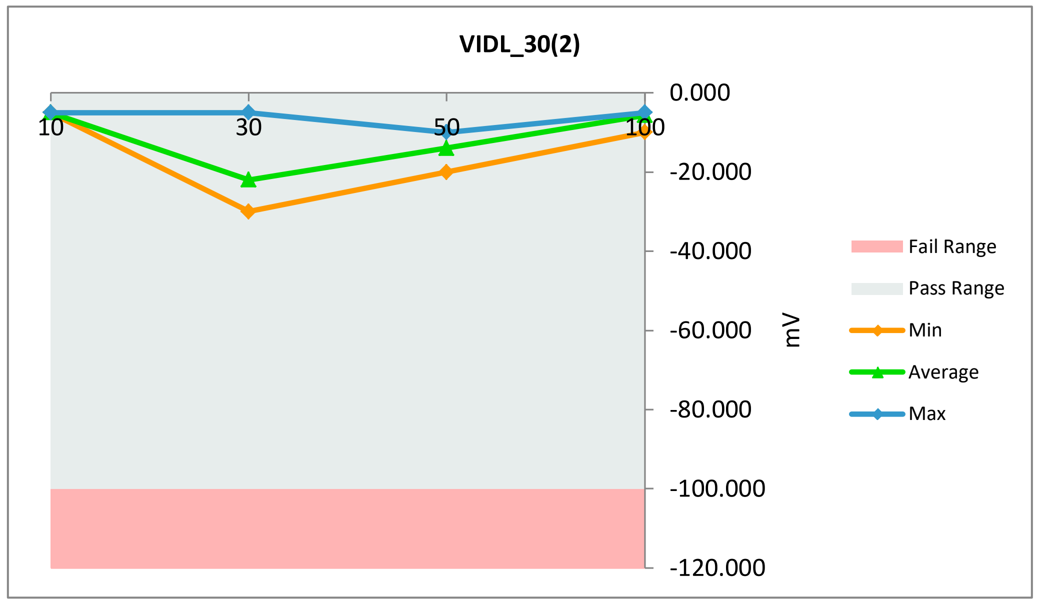
	VIDL_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-10.000	-5.000	-5.000
10	2	-15.000	-5.000	-10.000
10	3	-15.000	-5.000	-10.000
10	4	-5.000	-5.000	0.000
10	5	-10.000	-5.000	-5.000
30	1	-25.000	-20.000	-5.000
30	2	-5.000	-5.000	0.000
30	3	-35.000	-30.000	-5.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-10.000	0.000
50	13	-25.000	-10.000	-15.000
50	14	-15.000	-10.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-5.000	-5.000	0.000
100	23	-15.000	-5.000	-10.000
100	24	-10.000	-5.000	-5.000
100	25	-25.000	-10.000	-15.000
100	26	-15.000	-5.000	-10.000
100	27	-20.000	-5.000	-15.000
100	28	-20.000	-10.000	-10.000
100	29	-10.000	-5.000	-5.000
100	30	-10.000	-5.000	-5.000
100	31	-15.000	-5.000	-10.000
100	32	-10.000	-5.000	-5.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-5.000	-10.000
100	35	-10.000	-5.000	-5.000
100	36	-20.000	-5.000	-15.000
100	37	-15.000	-5.000	-10.000
100	38	-15.000	-5.000	-10.000
100	39	-5.000	-5.000	0.000
100	41	-20.000	-10.000	-10.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-14.865	-8.919	-5.946
	Min	-35.000	-30.000	-15.000
	Std Dev	7.948	7.278	5.632



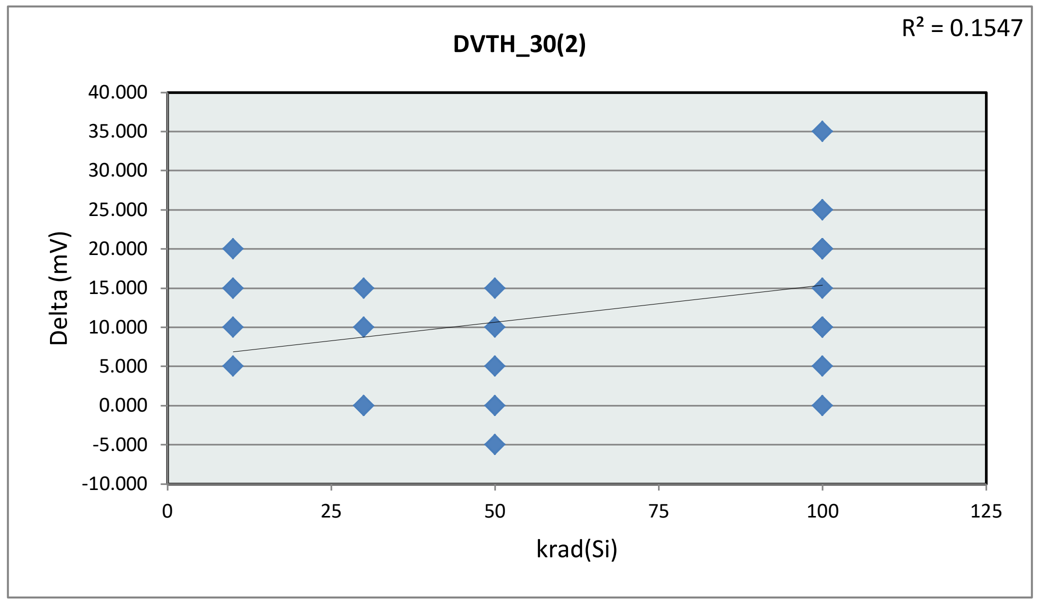
	VIDL_30(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit		mV
Min Limit	-100	mV

krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-20.000	-10.000
Average	-5.000	-22.000	-14.000	-5.682
Max	-5.000	-5.000	-10.000	-5.000
UL				

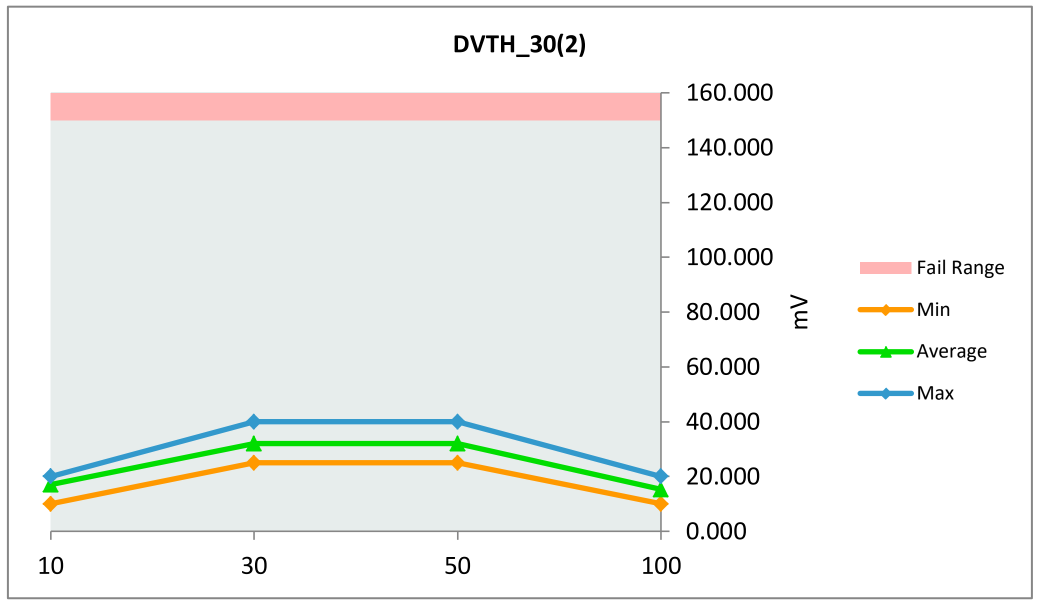


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	35.000	20.000	15.000
10	2	30.000	10.000	20.000
10	3	30.000	15.000	15.000
10	4	30.000	20.000	10.000
10	5	25.000	20.000	5.000
30	1	40.000	25.000	15.000
30	2	30.000	30.000	0.000
30	3	50.000	40.000	10.000
30	4	30.000	30.000	0.000
30	5	35.000	35.000	0.000
50	11	40.000	25.000	15.000
50	12	35.000	40.000	-5.000
50	13	40.000	35.000	5.000
50	14	35.000	35.000	0.000
50	15	35.000	25.000	10.000
100	22	20.000	15.000	5.000
100	23	40.000	15.000	25.000
100	24	25.000	15.000	10.000
100	25	30.000	20.000	10.000
100	26	35.000	15.000	20.000
100	27	50.000	15.000	35.000
100	28	35.000	15.000	20.000
100	29	30.000	20.000	10.000
100	30	30.000	15.000	15.000
100	31	35.000	15.000	20.000
100	32	35.000	15.000	20.000
100	33	30.000	20.000	10.000
100	34	35.000	15.000	20.000
100	35	35.000	15.000	20.000
100	36	30.000	10.000	20.000
100	37	40.000	15.000	25.000
100	38	30.000	10.000	20.000
100	39	25.000	15.000	10.000
100	41	25.000	15.000	10.000
100	42	25.000	15.000	10.000
100	43	30.000	10.000	20.000
100	44	20.000	20.000	0.000
	Max	50.000	40.000	35.000
	Average	32.703	20.000	12.703
	Min	20.000	10.000	-5.000
	Std Dev	6.728	8.416	8.708

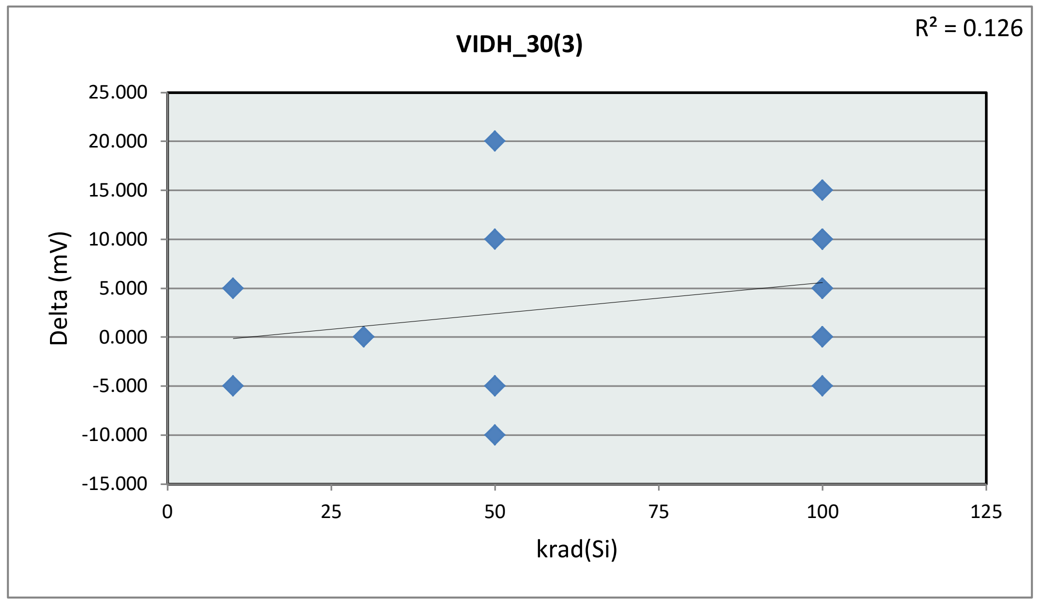


	DVTH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	25.000	25.000	10.000
Average	17.000	32.000	32.000	15.227
Max	20.000	40.000	40.000	20.000
UL	150.000	150.000	150.000	150.000

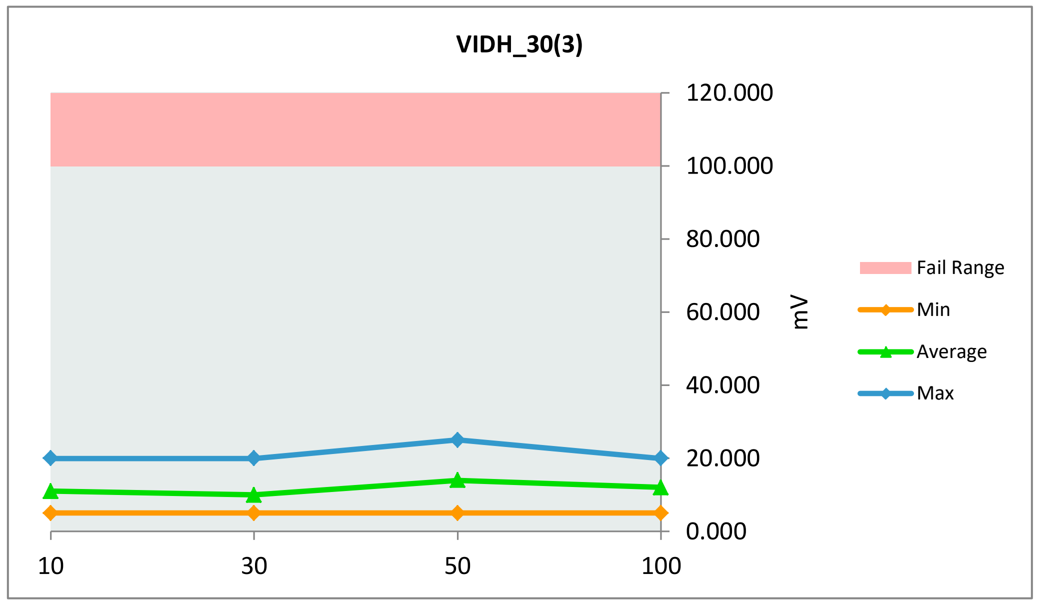


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	25.000	20.000	5.000
10	2	10.000	5.000	5.000
10	3	5.000	10.000	-5.000
10	4	5.000	10.000	-5.000
10	5	15.000	10.000	5.000
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	5.000	0.000
30	4	20.000	20.000	0.000
30	5	15.000	15.000	0.000
50	11	25.000	5.000	20.000
50	12	15.000	20.000	-5.000
50	13	15.000	5.000	10.000
50	14	20.000	25.000	-5.000
50	15	5.000	15.000	-10.000
100	22	5.000	5.000	0.000
100	23	25.000	15.000	10.000
100	24	20.000	15.000	5.000
100	25	30.000	20.000	10.000
100	26	35.000	20.000	15.000
100	27	20.000	15.000	5.000
100	28	5.000	5.000	0.000
100	29	15.000	10.000	5.000
100	30	25.000	10.000	15.000
100	31	5.000	5.000	0.000
100	32	20.000	15.000	5.000
100	33	25.000	15.000	10.000
100	34	30.000	20.000	10.000
100	35	15.000	10.000	5.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	20.000	15.000	5.000
100	39	15.000	10.000	5.000
100	41	20.000	10.000	10.000
100	42	15.000	10.000	5.000
100	43	5.000	10.000	-5.000
100	44	15.000	15.000	0.000
	Max	35.000	25.000	20.000
	Average	15.676	11.892	3.784
	Min	5.000	5.000	-10.000
	Std Dev	8.593	5.695	6.498

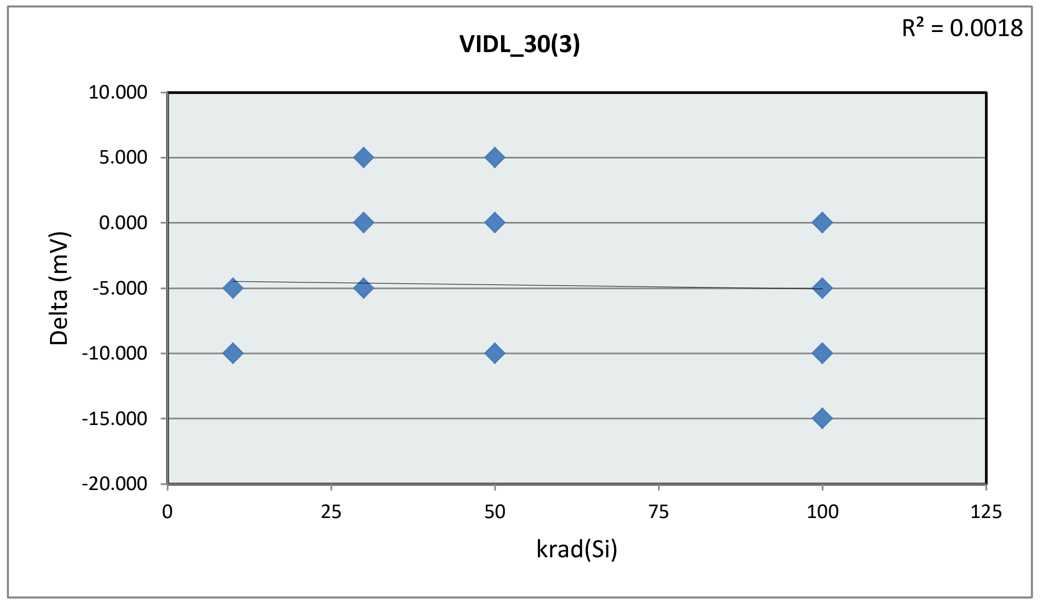


	VIDH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	11.000	10.000	14.000	12.045
Max	20.000	20.000	25.000	20.000
UL	100.000	100.000	100.000	100.000

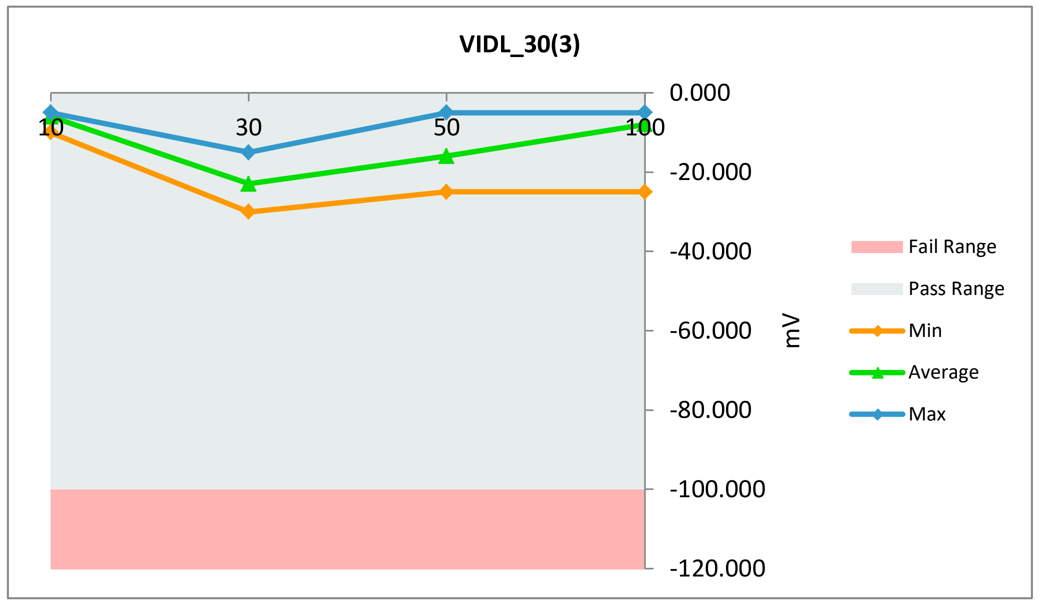


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_30(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	-15.000	-5.000	-10.000
10	2	-20.000	-10.000	-10.000
10	3	-15.000	-5.000	-10.000
10	4	-15.000	-5.000	-10.000
10	5	-10.000	-5.000	-5.000
30	1	-30.000	-30.000	0.000
30	2	-15.000	-15.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-20.000	-15.000	-5.000
30	5	-20.000	-25.000	5.000
50	11	-15.000	-15.000	0.000
50	12	-25.000	-15.000	-10.000
50	13	-20.000	-25.000	5.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-20.000	-10.000
100	22	-15.000	-5.000	-10.000
100	23	-5.000	-5.000	0.000
100	24	-5.000	-5.000	0.000
100	25	-20.000	-10.000	-10.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-25.000	-5.000
100	28	-30.000	-20.000	-10.000
100	29	-15.000	-5.000	-10.000
100	30	-5.000	-5.000	0.000
100	31	-25.000	-10.000	-15.000
100	32	-15.000	-5.000	-10.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-10.000	-10.000
100	36	-25.000	-15.000	-10.000
100	37	-25.000	-10.000	-15.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	41	-10.000	-5.000	-5.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-15.676	-10.811	-4.865
	Min	-30.000	-30.000	-15.000
	Std Dev	8.832	7.951	5.588

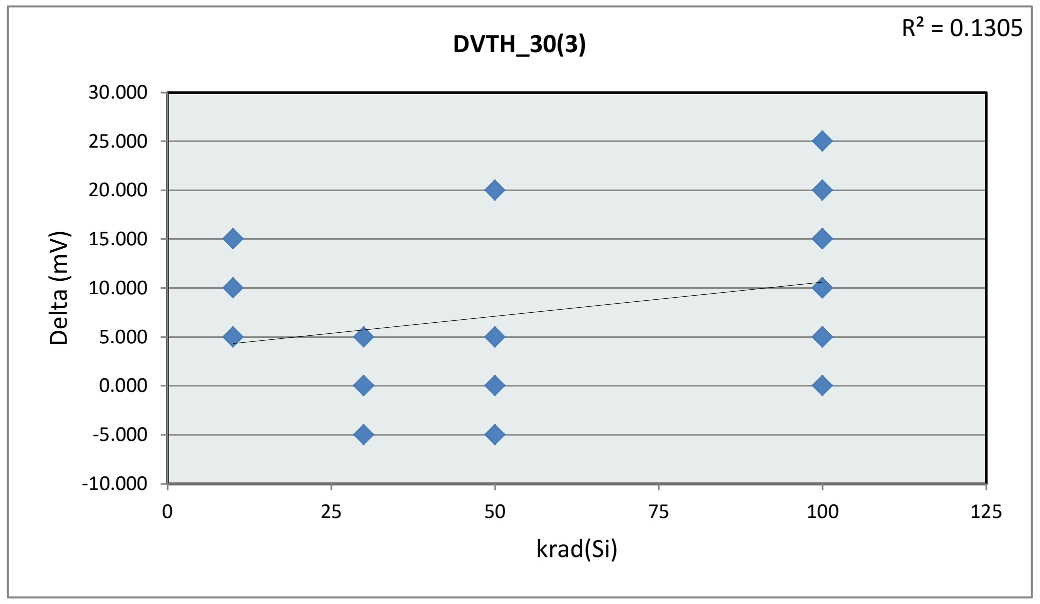


	VIDL_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-10.000	-30.000	-25.000	-25.000
Average	-6.000	-23.000	-16.000	-7.955
Max	-5.000	-15.000	-5.000	-5.000
UL				

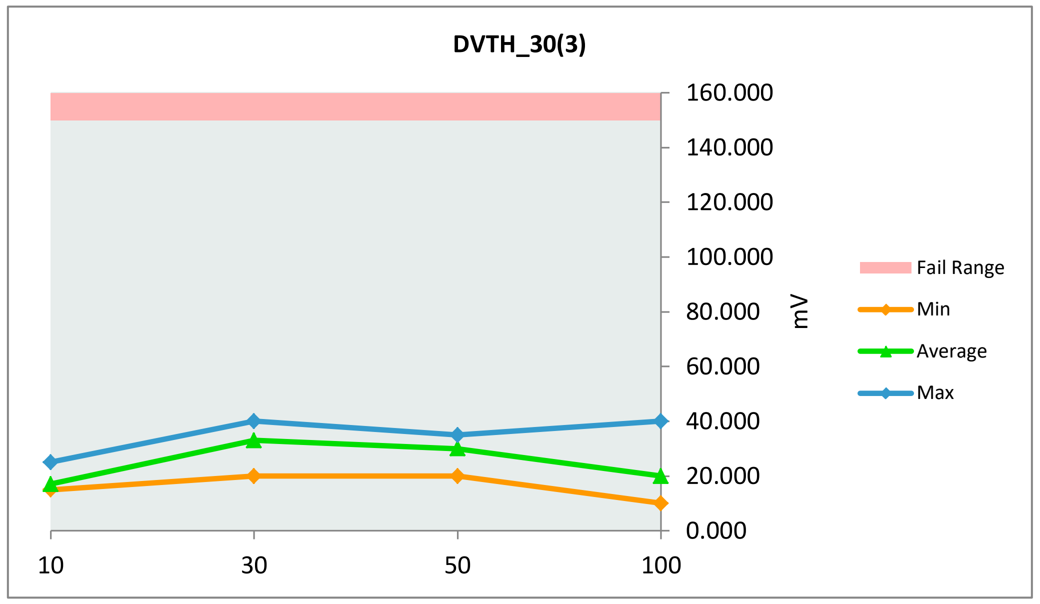


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	40.000	25.000	15.000
10	2	30.000	15.000	15.000
10	3	20.000	15.000	5.000
10	4	20.000	15.000	5.000
10	5	25.000	15.000	10.000
30	1	35.000	35.000	0.000
30	2	20.000	20.000	0.000
30	3	35.000	35.000	0.000
30	4	40.000	35.000	5.000
30	5	35.000	40.000	-5.000
50	11	40.000	20.000	20.000
50	12	40.000	35.000	5.000
50	13	35.000	30.000	5.000
50	14	25.000	30.000	-5.000
50	15	35.000	35.000	0.000
100	22	20.000	10.000	10.000
100	23	30.000	20.000	10.000
100	24	25.000	20.000	5.000
100	25	50.000	30.000	20.000
100	26	40.000	25.000	15.000
100	27	50.000	40.000	10.000
100	28	35.000	25.000	10.000
100	29	30.000	15.000	15.000
100	30	30.000	15.000	15.000
100	31	30.000	15.000	15.000
100	32	35.000	20.000	15.000
100	33	30.000	20.000	10.000
100	34	35.000	25.000	10.000
100	35	35.000	20.000	15.000
100	36	30.000	20.000	10.000
100	37	45.000	20.000	25.000
100	38	25.000	20.000	5.000
100	39	20.000	15.000	5.000
100	41	30.000	15.000	15.000
100	42	20.000	15.000	5.000
100	43	20.000	15.000	5.000
100	44	20.000	20.000	0.000
	Max	50.000	40.000	25.000
	Average	31.351	22.703	8.649
	Min	20.000	10.000	-5.000
	Std Dev	8.470	8.215	7.036

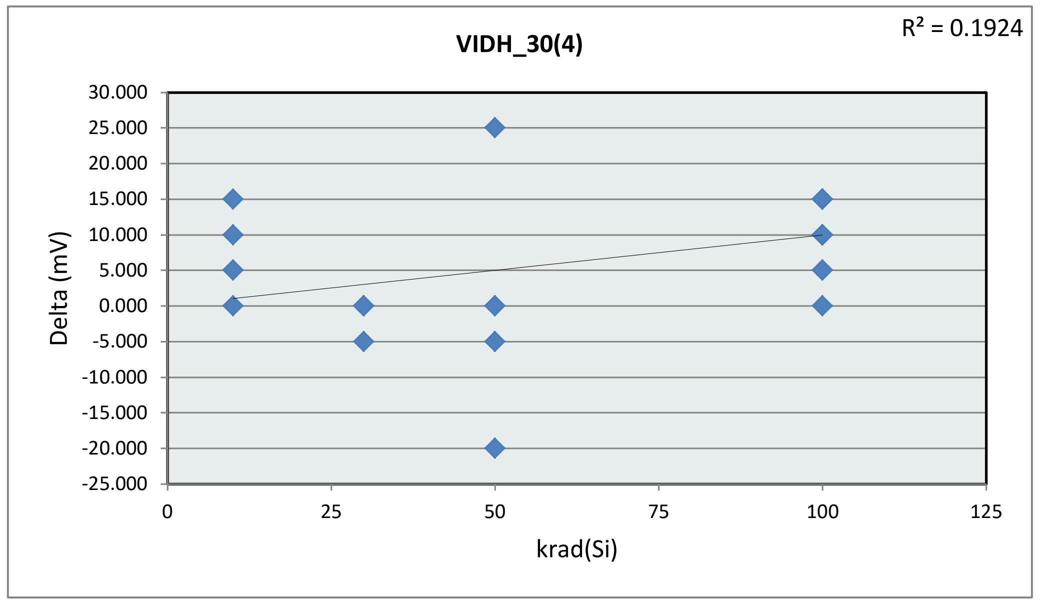


	DVTH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	20.000	20.000	10.000
Average	17.000	33.000	30.000	20.000
Max	25.000	40.000	35.000	40.000
UL	150.000	150.000	150.000	150.000

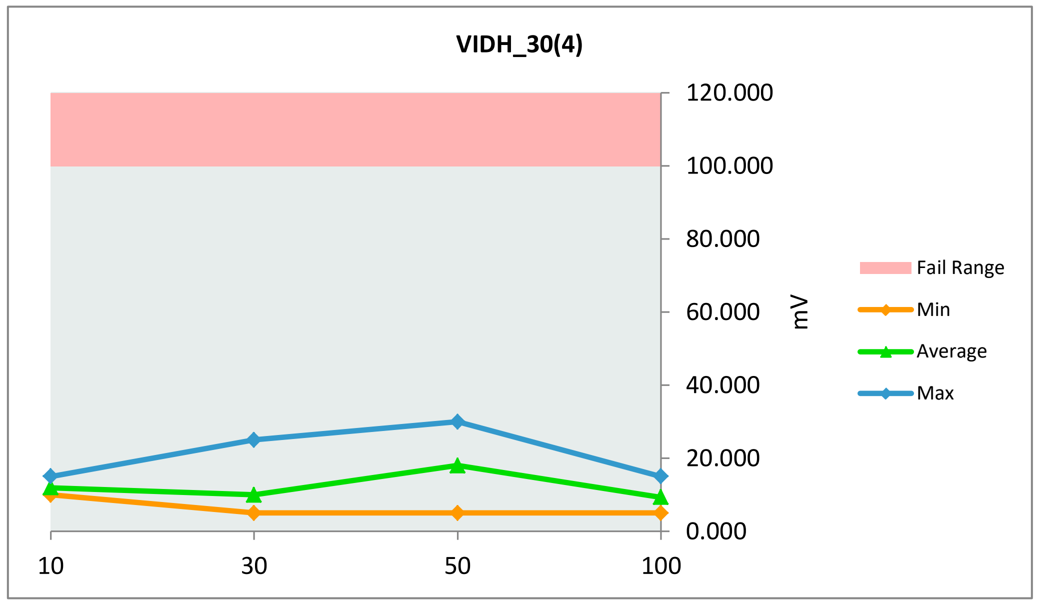


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_30(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	15.000	5.000
10	2	20.000	10.000	10.000
10	3	15.000	15.000	0.000
10	4	25.000	10.000	15.000
10	5	15.000	10.000	5.000
30	1	5.000	5.000	0.000
30	2	25.000	25.000	0.000
30	3	5.000	10.000	-5.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	30.000	30.000	0.000
50	13	5.000	25.000	-20.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	20.000	10.000	10.000
100	23	25.000	10.000	15.000
100	24	20.000	10.000	10.000
100	25	25.000	10.000	15.000
100	26	20.000	10.000	10.000
100	27	25.000	10.000	15.000
100	28	20.000	5.000	15.000
100	29	20.000	10.000	10.000
100	30	20.000	10.000	10.000
100	31	15.000	10.000	5.000
100	32	25.000	10.000	15.000
100	33	25.000	15.000	10.000
100	34	25.000	10.000	15.000
100	35	25.000	10.000	15.000
100	36	10.000	5.000	5.000
100	37	25.000	10.000	15.000
100	38	15.000	5.000	10.000
100	39	20.000	10.000	10.000
100	41	5.000	5.000	0.000
100	42	20.000	10.000	10.000
100	43	10.000	5.000	5.000
100	44	25.000	15.000	10.000
	Max	30.000	30.000	25.000
	Average	18.108	10.946	7.162
	Min	5.000	5.000	-20.000
	Std Dev	7.849	6.218	8.211

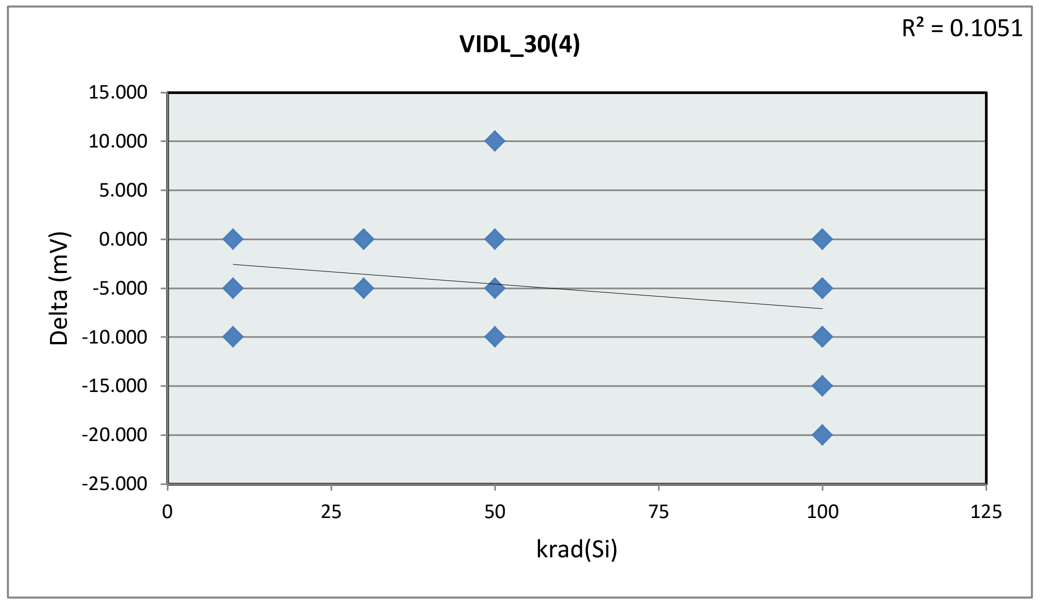


	VIDH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	12.000	10.000	18.000	9.318
Max	15.000	25.000	30.000	15.000
UL	100.000	100.000	100.000	100.000

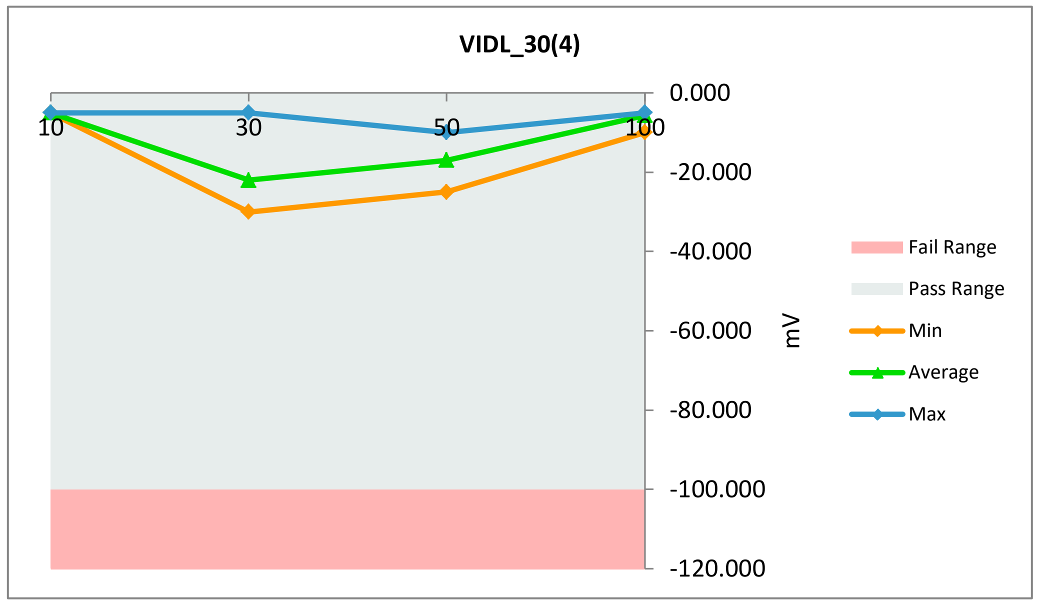


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-10.000	-5.000	-5.000
10	2	-15.000	-5.000	-10.000
10	3	-15.000	-5.000	-10.000
10	4	-5.000	-5.000	0.000
10	5	-10.000	-5.000	-5.000
30	1	-20.000	-20.000	0.000
30	2	-5.000	-5.000	0.000
30	3	-35.000	-30.000	-5.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-15.000	-25.000	10.000
50	12	-15.000	-10.000	-5.000
50	13	-25.000	-15.000	-10.000
50	14	-10.000	-10.000	0.000
50	15	-30.000	-25.000	-5.000
100	22	-10.000	-5.000	-5.000
100	23	-15.000	-5.000	-10.000
100	24	-10.000	-5.000	-5.000
100	25	-25.000	-5.000	-20.000
100	26	-15.000	-5.000	-10.000
100	27	-20.000	-5.000	-15.000
100	28	-25.000	-10.000	-15.000
100	29	-10.000	-5.000	-5.000
100	30	-10.000	-5.000	-5.000
100	31	-10.000	-5.000	-5.000
100	32	-10.000	-5.000	-5.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-5.000	-10.000
100	35	-10.000	-5.000	-5.000
100	36	-20.000	-10.000	-10.000
100	37	-15.000	-5.000	-10.000
100	38	-15.000	-5.000	-10.000
100	39	-5.000	-5.000	0.000
100	41	-20.000	-10.000	-10.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-15.000	-9.324	-5.676
	Min	-35.000	-30.000	-20.000
	Std Dev	7.817	7.832	5.672

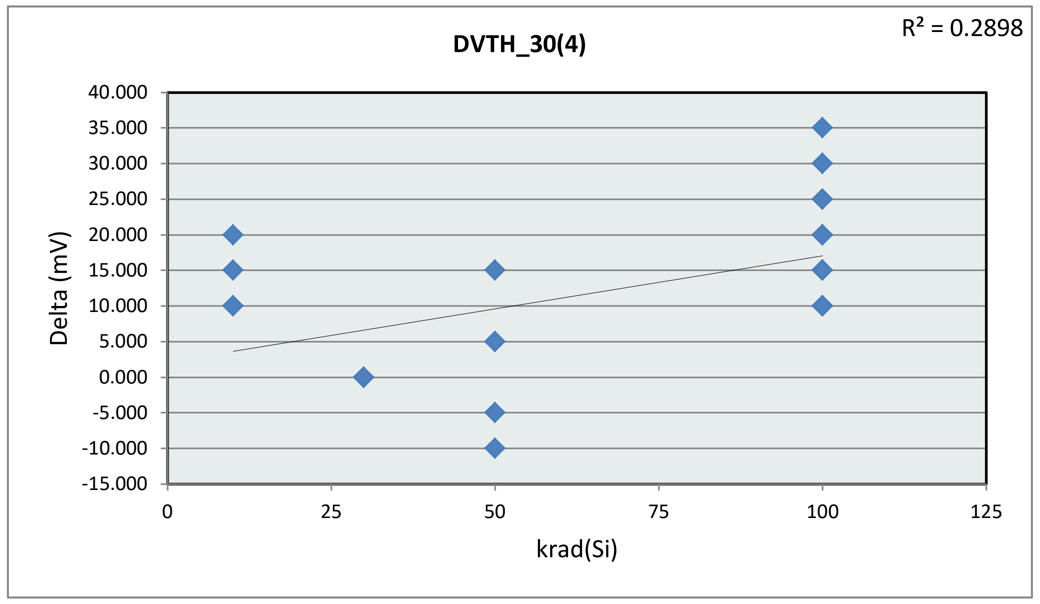


	VIDL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-25.000	-10.000
Average	-5.000	-22.000	-17.000	-5.682
Max	-5.000	-5.000	-10.000	-5.000
UL				

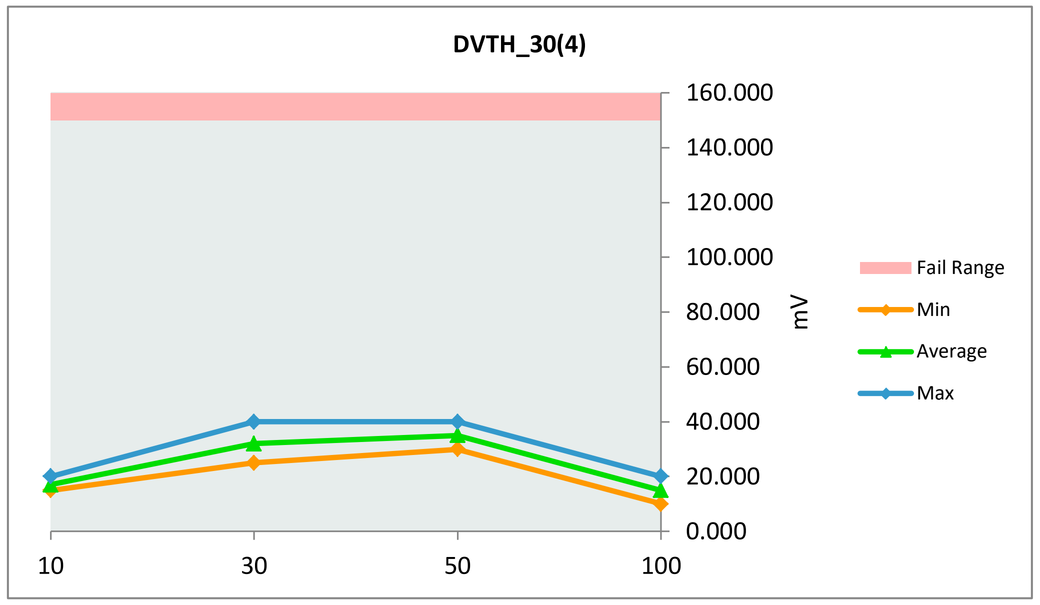


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	30.000	20.000	10.000
10	2	35.000	15.000	20.000
10	3	30.000	20.000	10.000
10	4	30.000	15.000	15.000
10	5	25.000	15.000	10.000
30	1	25.000	25.000	0.000
30	2	30.000	30.000	0.000
30	3	40.000	40.000	0.000
30	4	30.000	30.000	0.000
30	5	35.000	35.000	0.000
50	11	45.000	30.000	15.000
50	12	45.000	40.000	5.000
50	13	30.000	40.000	-10.000
50	14	30.000	35.000	-5.000
50	15	35.000	30.000	5.000
100	22	30.000	15.000	15.000
100	23	40.000	15.000	25.000
100	24	30.000	15.000	15.000
100	25	50.000	15.000	35.000
100	26	35.000	15.000	20.000
100	27	45.000	15.000	30.000
100	28	45.000	15.000	30.000
100	29	30.000	15.000	15.000
100	30	30.000	15.000	15.000
100	31	25.000	15.000	10.000
100	32	35.000	15.000	20.000
100	33	30.000	20.000	10.000
100	34	40.000	15.000	25.000
100	35	35.000	15.000	20.000
100	36	30.000	15.000	15.000
100	37	40.000	15.000	25.000
100	38	30.000	10.000	20.000
100	39	25.000	15.000	10.000
100	41	25.000	15.000	10.000
100	42	25.000	15.000	10.000
100	43	25.000	10.000	15.000
100	44	30.000	20.000	10.000
	Max	50.000	40.000	35.000
	Average	33.108	20.270	12.838
	Min	25.000	10.000	-10.000
	Std Dev	6.806	8.815	10.106

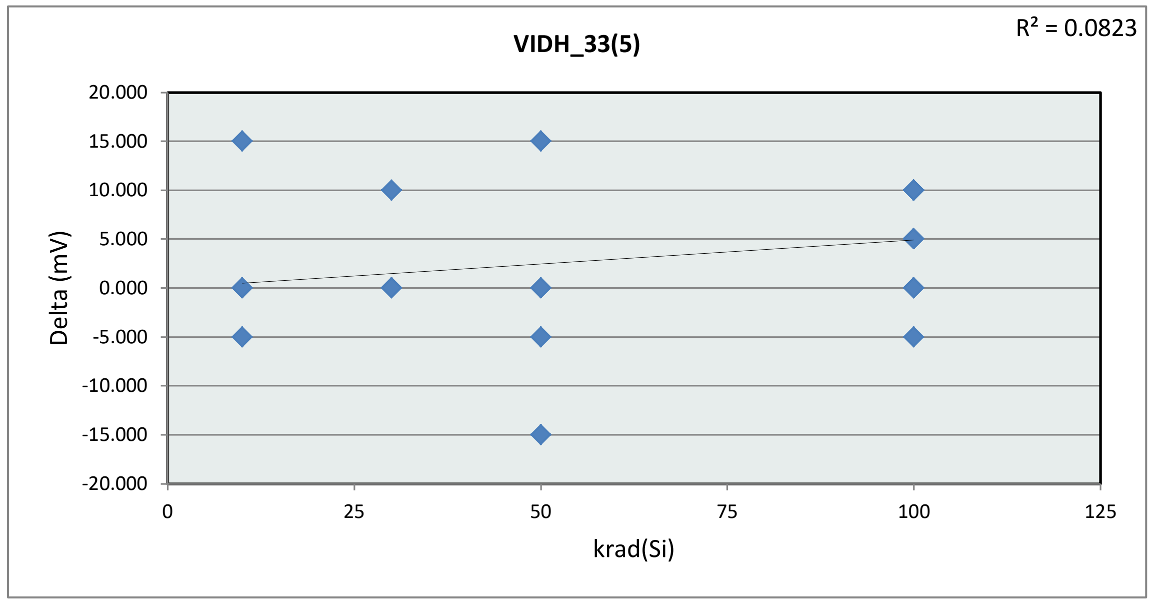


	DVTH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	30.000	10.000
Average	17.000	32.000	35.000	15.000
Max	20.000	40.000	40.000	20.000
UL	150.000	150.000	150.000	150.000

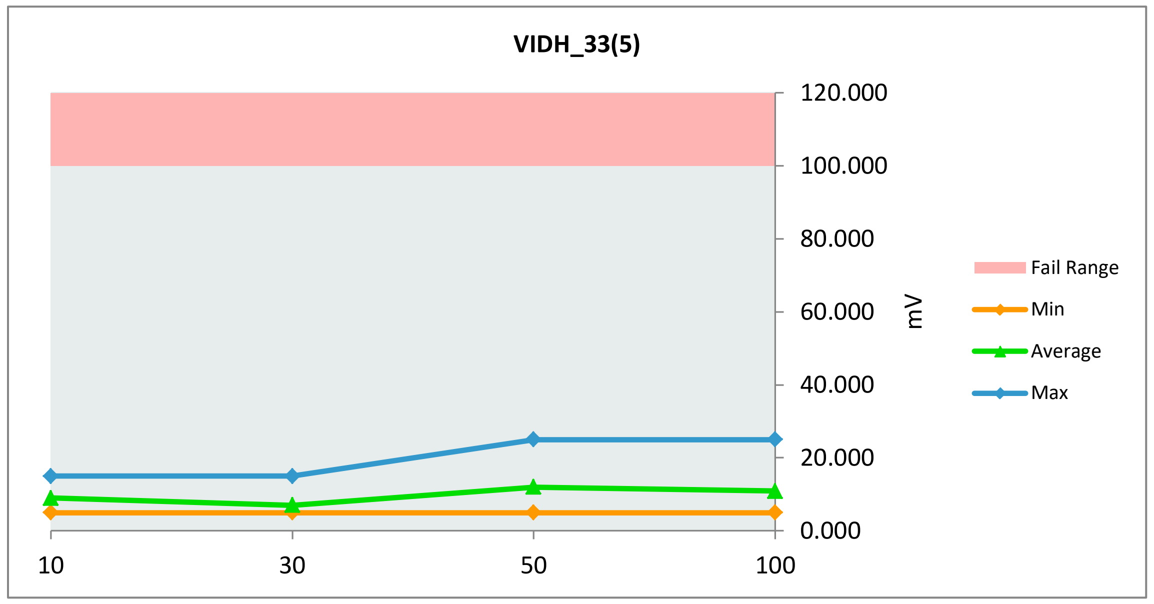


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	25.000	10.000	15.000
10	2	5.000	5.000	0.000
10	3	5.000	10.000	-5.000
10	4	5.000	5.000	0.000
10	5	15.000	15.000	0.000
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	5.000	0.000
30	4	15.000	15.000	0.000
30	5	15.000	5.000	10.000
50	11	20.000	5.000	15.000
50	12	5.000	20.000	-15.000
50	13	5.000	5.000	0.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	25.000	15.000	10.000
100	24	15.000	10.000	5.000
100	25	30.000	20.000	10.000
100	26	30.000	25.000	5.000
100	27	15.000	10.000	5.000
100	28	5.000	5.000	0.000
100	29	15.000	10.000	5.000
100	30	20.000	15.000	5.000
100	31	5.000	5.000	0.000
100	32	15.000	10.000	5.000
100	33	25.000	15.000	10.000
100	34	25.000	15.000	10.000
100	35	15.000	10.000	5.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	20.000	10.000	10.000
100	39	5.000	10.000	-5.000
100	41	20.000	10.000	10.000
100	42	15.000	10.000	5.000
100	43	5.000	5.000	0.000
100	44	20.000	10.000	10.000
	Max	30.000	25.000	15.000
	Average	13.784	10.270	3.514
	Min	5.000	5.000	-15.000
	Std Dev	8.284	5.645	6.221

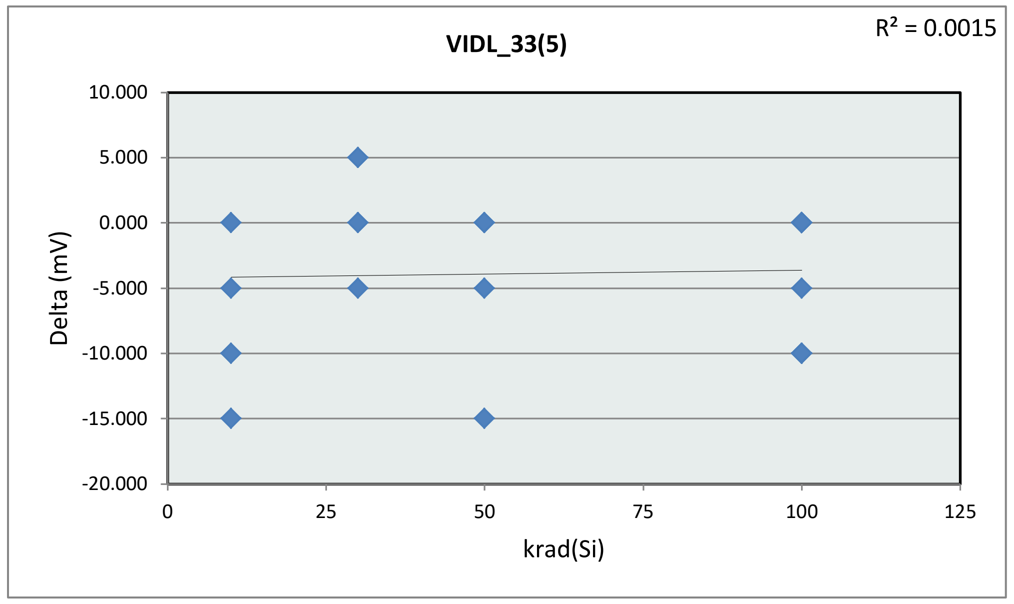


	VIDH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	9.000	7.000	12.000	10.909
Max	15.000	15.000	25.000	25.000
UL	100.000	100.000	100.000	100.000

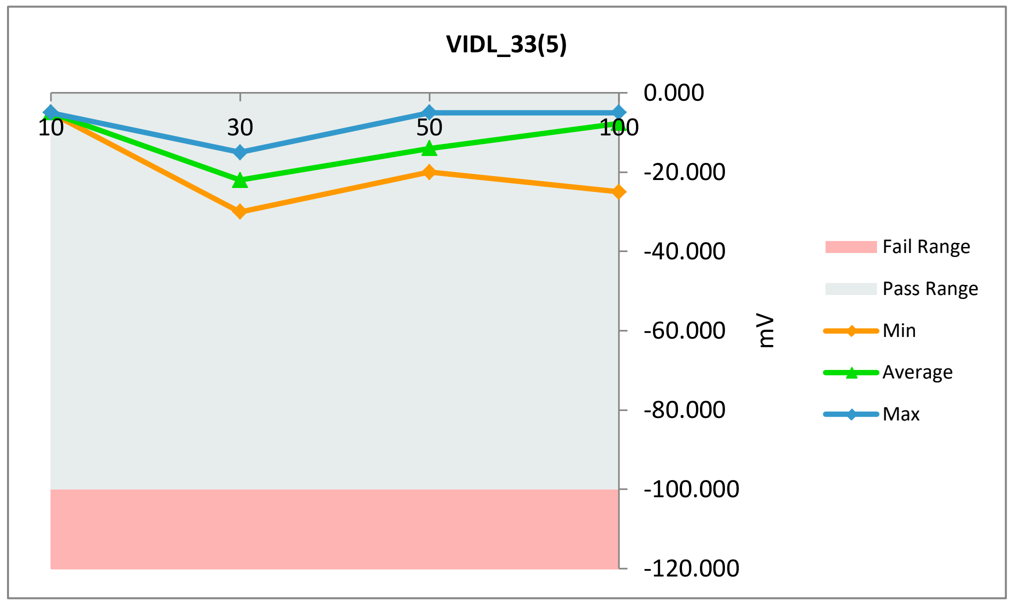


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-15.000	-5.000	-10.000
10	2	-20.000	-5.000	-15.000
10	3	-10.000	-5.000	-5.000
10	4	-15.000	-5.000	-10.000
10	5	-5.000	-5.000	0.000
30	1	-30.000	-30.000	0.000
30	2	-10.000	-15.000	5.000
30	3	-30.000	-25.000	-5.000
30	4	-15.000	-20.000	5.000
30	5	-20.000	-20.000	0.000
50	11	-15.000	-15.000	0.000
50	12	-20.000	-15.000	-5.000
50	13	-20.000	-20.000	0.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-15.000	-15.000
100	22	-5.000	-5.000	0.000
100	23	-5.000	-5.000	0.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-5.000	-10.000
100	26	-5.000	-5.000	0.000
100	27	-35.000	-25.000	-10.000
100	28	-30.000	-20.000	-10.000
100	29	-5.000	-5.000	0.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-10.000	-10.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-10.000	-10.000
100	36	-25.000	-15.000	-10.000
100	37	-20.000	-10.000	-10.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	41	-10.000	-5.000	-5.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-13.919	-10.135	-3.784
	Min	-35.000	-30.000	-15.000
	Std Dev	9.290	7.311	5.452

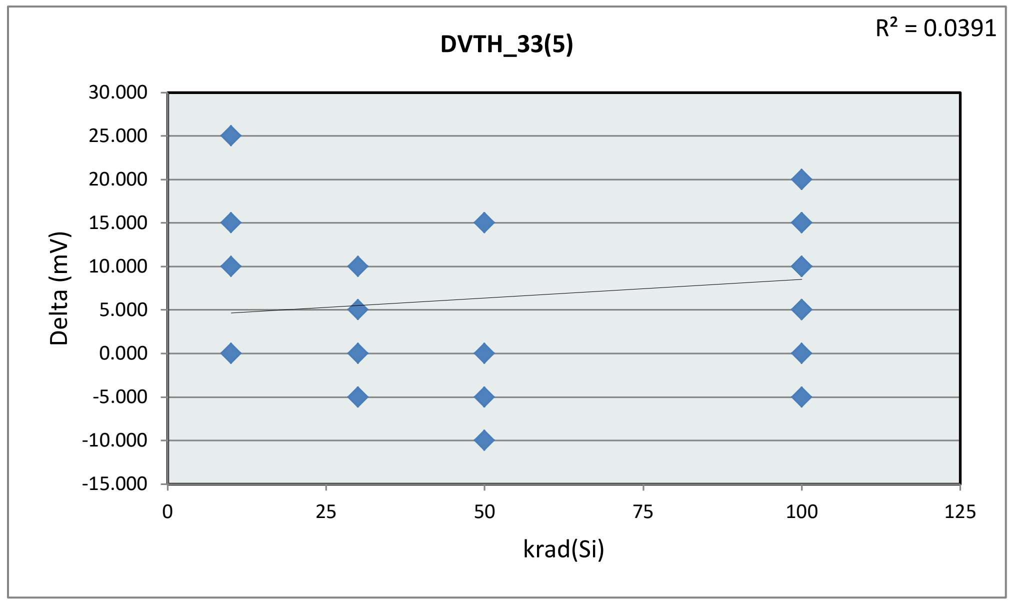


	VIDL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-20.000	-25.000
Average	-5.000	-22.000	-14.000	-7.727
Max	-5.000	-15.000	-5.000	-5.000
UL				

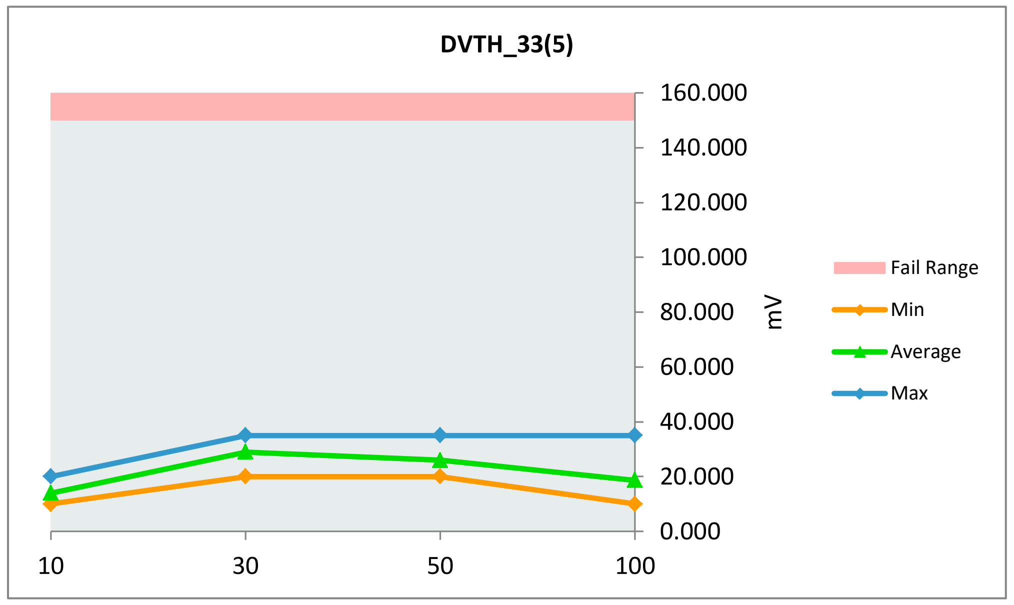


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	40.000	15.000	25.000
10	2	25.000	10.000	15.000
10	3	15.000	15.000	0.000
10	4	20.000	10.000	10.000
10	5	20.000	20.000	0.000
30	1	35.000	35.000	0.000
30	2	15.000	20.000	-5.000
30	3	35.000	30.000	5.000
30	4	30.000	35.000	-5.000
30	5	35.000	25.000	10.000
50	11	35.000	20.000	15.000
50	12	25.000	35.000	-10.000
50	13	25.000	25.000	0.000
50	14	25.000	30.000	-5.000
50	15	35.000	20.000	15.000
100	22	10.000	10.000	0.000
100	23	30.000	20.000	10.000
100	24	20.000	15.000	5.000
100	25	45.000	25.000	20.000
100	26	35.000	30.000	5.000
100	27	50.000	35.000	15.000
100	28	35.000	25.000	10.000
100	29	20.000	15.000	5.000
100	30	25.000	20.000	5.000
100	31	25.000	15.000	10.000
100	32	20.000	15.000	5.000
100	33	30.000	20.000	10.000
100	34	30.000	20.000	10.000
100	35	35.000	20.000	15.000
100	36	30.000	20.000	10.000
100	37	40.000	20.000	20.000
100	38	25.000	15.000	10.000
100	39	10.000	15.000	-5.000
100	41	30.000	15.000	15.000
100	42	20.000	15.000	5.000
100	43	20.000	10.000	10.000
100	44	25.000	15.000	10.000
	Max	50.000	35.000	25.000
	Average	27.703	20.405	7.297
	Min	10.000	10.000	-10.000
	Std Dev	9.098	7.395	7.958

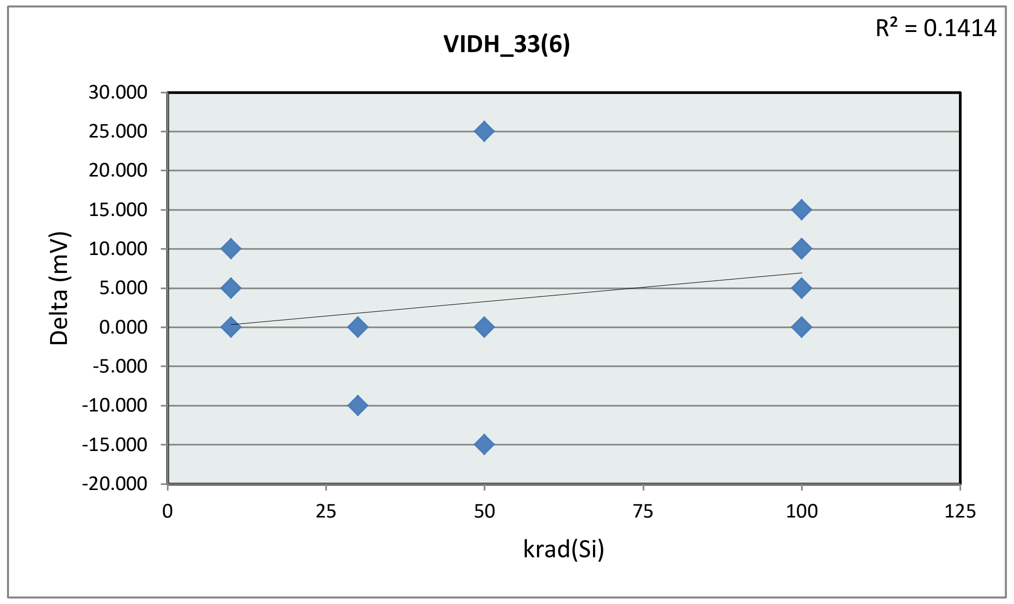


	DVTH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	20.000	10.000
Average	14.000	29.000	26.000	18.636
Max	20.000	35.000	35.000	35.000
UL	150.000	150.000	150.000	150.000

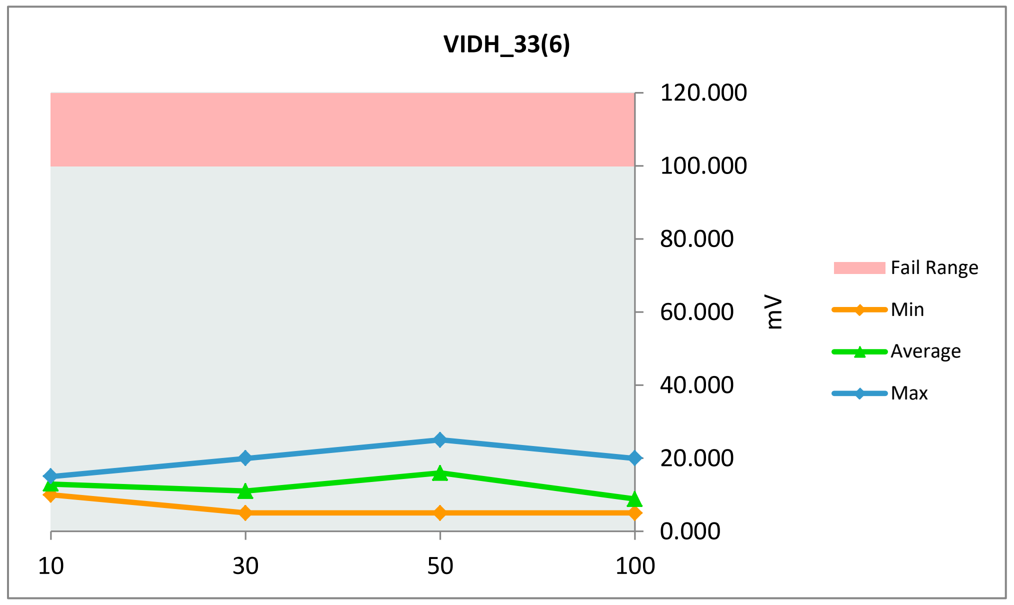


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	20.000	10.000	10.000
10	2	15.000	10.000	5.000
10	3	15.000	15.000	0.000
10	4	20.000	15.000	5.000
10	5	15.000	15.000	0.000
30	1	10.000	10.000	0.000
30	2	20.000	20.000	0.000
30	3	5.000	5.000	0.000
30	4	5.000	15.000	-10.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	25.000	25.000	0.000
50	13	10.000	25.000	-15.000
50	14	20.000	20.000	0.000
50	15	5.000	5.000	0.000
100	22	15.000	10.000	5.000
100	23	20.000	10.000	10.000
100	24	15.000	5.000	10.000
100	25	5.000	5.000	0.000
100	26	20.000	10.000	10.000
100	27	25.000	10.000	15.000
100	28	15.000	5.000	10.000
100	29	20.000	10.000	10.000
100	30	15.000	10.000	5.000
100	31	20.000	10.000	10.000
100	32	20.000	10.000	10.000
100	33	20.000	10.000	10.000
100	34	20.000	10.000	10.000
100	35	20.000	10.000	10.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	5.000	5.000	0.000
100	39	20.000	10.000	10.000
100	41	5.000	5.000	0.000
100	42	20.000	10.000	10.000
100	43	5.000	5.000	0.000
100	44	25.000	20.000	5.000
	Max	30.000	25.000	25.000
	Average	15.541	10.676	4.865
	Min	5.000	5.000	-15.000
	Std Dev	7.148	5.548	7.119



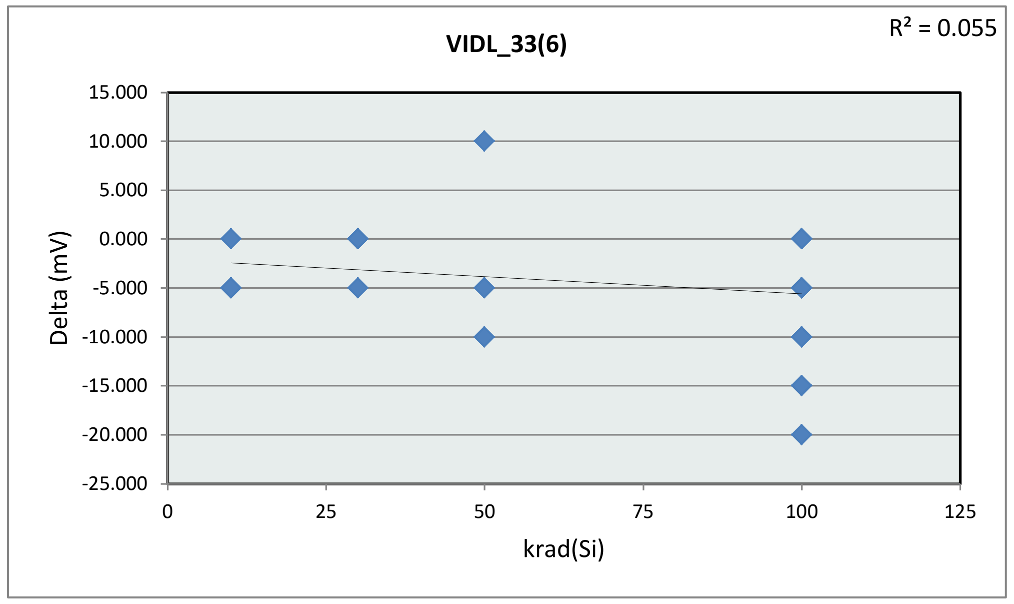
	VIDH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	13.000	11.000	16.000	8.864
Max	15.000	20.000	25.000	20.000
UL	100.000	100.000	100.000	100.000



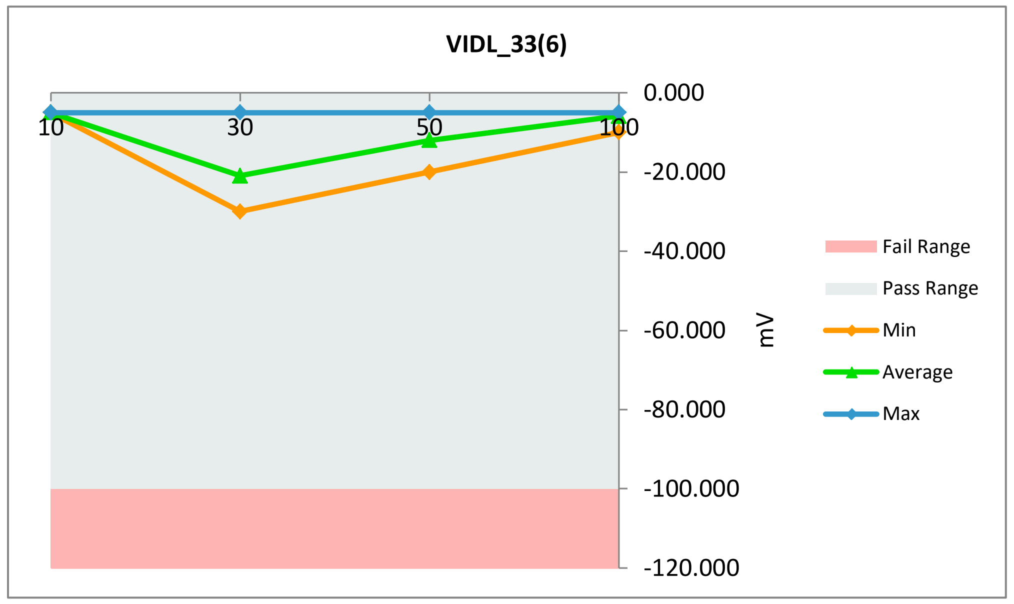
HDR Biased TID Report
SN55LVCP22A-SP

	VIDL_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-10.000	-5.000	-5.000
10	2	-10.000	-5.000	-5.000
10	3	-10.000	-5.000	-5.000
10	4	-5.000	-5.000	0.000
10	5	-10.000	-5.000	-5.000
30	1	-20.000	-15.000	-5.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-20.000	-10.000	-10.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-10.000	-5.000	-5.000
100	23	-10.000	-5.000	-5.000
100	24	-10.000	-5.000	-5.000
100	25	-20.000	-5.000	-15.000
100	26	-10.000	-5.000	-5.000
100	27	-25.000	-5.000	-20.000
100	28	-20.000	-10.000	-10.000
100	29	-5.000	-5.000	0.000
100	30	-10.000	-5.000	-5.000
100	31	-10.000	-5.000	-5.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-5.000	-10.000
100	35	-10.000	-5.000	-5.000
100	36	-15.000	-10.000	-5.000
100	37	-15.000	-5.000	-10.000
100	38	-15.000	-10.000	-5.000
100	39	-5.000	-5.000	0.000
100	41	-20.000	-5.000	-15.000
100	42	-5.000	-5.000	0.000
100	43	-10.000	-10.000	0.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-13.243	-8.649	-4.595
	Min	-30.000	-30.000	-20.000
	Std Dev	7.566	7.134	5.449

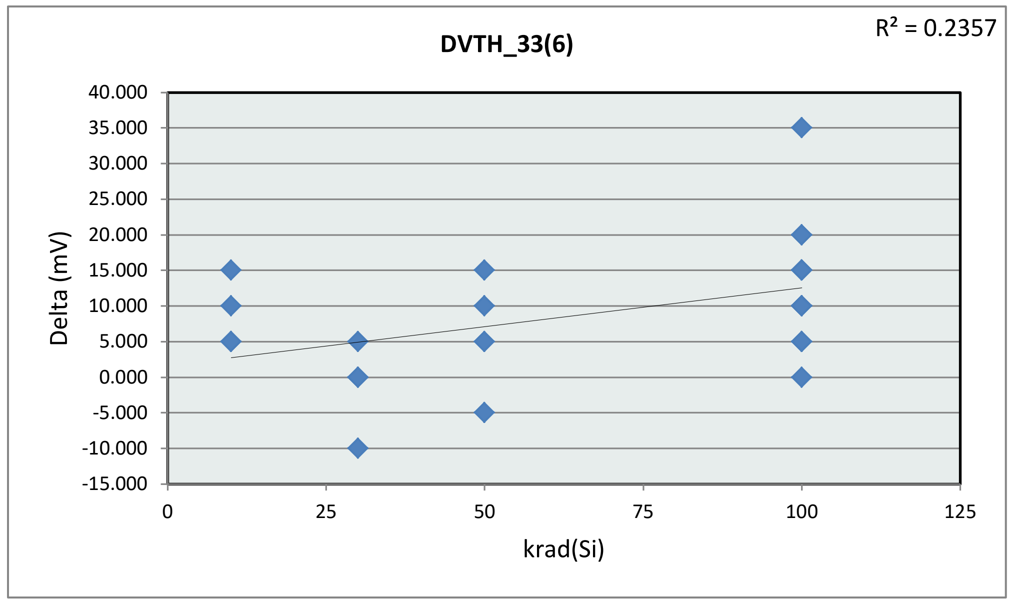


	VIDL_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-20.000	-10.000
Average	-5.000	-21.000	-12.000	-5.909
Max	-5.000	-5.000	-5.000	-5.000
UL				

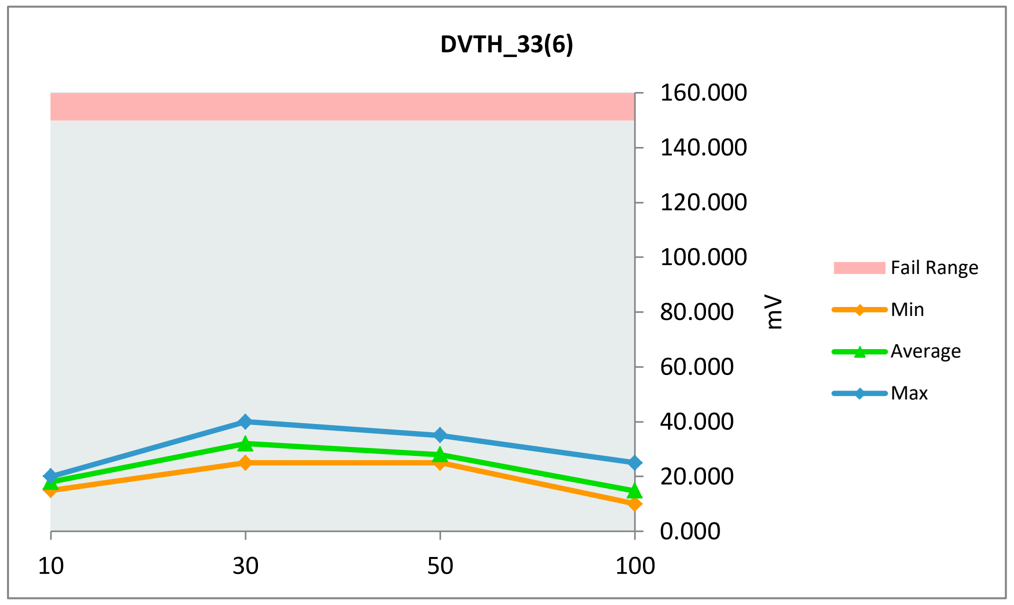


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	30.000	15.000	15.000
10	2	25.000	15.000	10.000
10	3	25.000	20.000	5.000
10	4	25.000	20.000	5.000
10	5	25.000	20.000	5.000
30	1	30.000	25.000	5.000
30	2	25.000	25.000	0.000
30	3	35.000	35.000	0.000
30	4	30.000	40.000	-10.000
30	5	35.000	35.000	0.000
50	11	40.000	25.000	15.000
50	12	35.000	30.000	5.000
50	13	30.000	35.000	-5.000
50	14	30.000	25.000	5.000
50	15	35.000	25.000	10.000
100	22	25.000	15.000	10.000
100	23	30.000	15.000	15.000
100	24	25.000	10.000	15.000
100	25	25.000	10.000	15.000
100	26	30.000	15.000	15.000
100	27	50.000	15.000	35.000
100	28	35.000	15.000	20.000
100	29	25.000	15.000	10.000
100	30	25.000	15.000	10.000
100	31	30.000	15.000	15.000
100	32	25.000	15.000	10.000
100	33	25.000	15.000	10.000
100	34	35.000	15.000	20.000
100	35	30.000	15.000	15.000
100	36	20.000	15.000	5.000
100	37	35.000	15.000	20.000
100	38	20.000	15.000	5.000
100	39	25.000	15.000	10.000
100	41	25.000	10.000	15.000
100	42	25.000	15.000	10.000
100	43	15.000	15.000	0.000
100	44	30.000	25.000	5.000
	Max	50.000	40.000	35.000
	Average	28.784	19.324	9.459
	Min	15.000	10.000	-10.000
	Std Dev	6.281	7.652	8.147



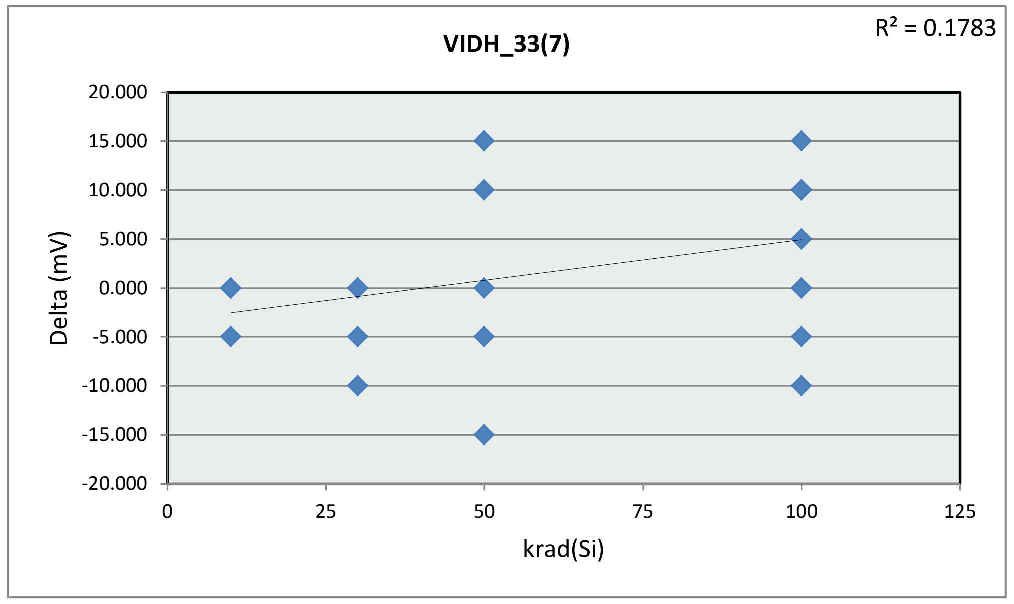
	DVTH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	25.000	10.000
Average	18.000	32.000	28.000	14.773
Max	20.000	40.000	35.000	25.000
UL	150.000	150.000	150.000	150.000



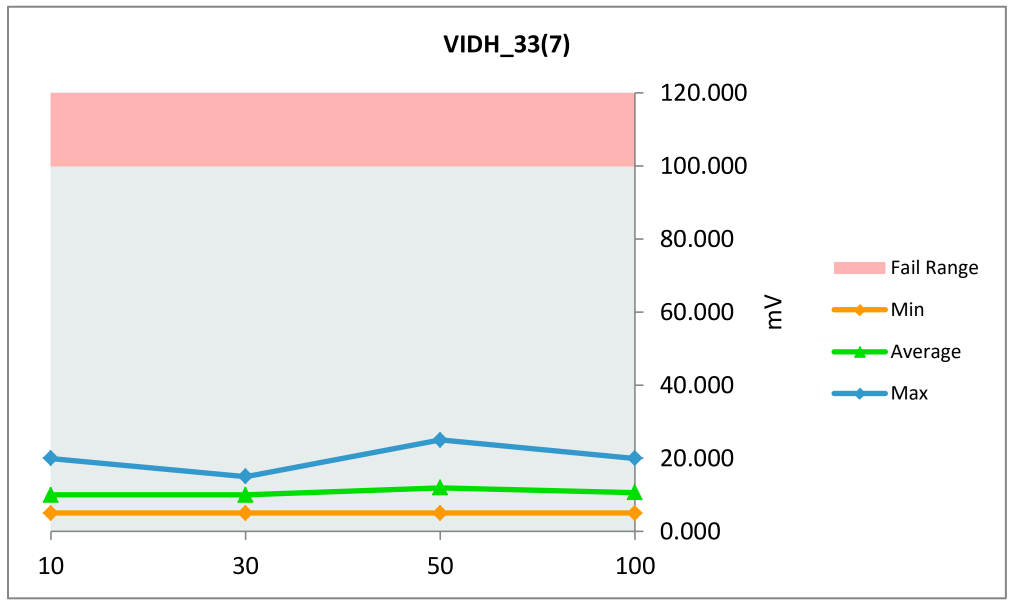
HDR Biased TID Report
SN55LVCP22A-SP

	VIDH_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	20.000	0.000
10	2	5.000	5.000	0.000
10	3	10.000	10.000	0.000
10	4	5.000	5.000	0.000
10	5	5.000	10.000	-5.000
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	10.000	-5.000
30	4	15.000	15.000	0.000
30	5	5.000	15.000	-10.000
50	11	20.000	5.000	15.000
50	12	5.000	20.000	-15.000
50	13	15.000	5.000	10.000
50	14	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	25.000	15.000	10.000
100	24	20.000	10.000	10.000
100	25	30.000	15.000	15.000
100	26	30.000	20.000	10.000
100	27	20.000	10.000	10.000
100	28	5.000	5.000	0.000
100	29	15.000	10.000	5.000
100	30	20.000	15.000	5.000
100	31	5.000	5.000	0.000
100	32	5.000	15.000	-10.000
100	33	25.000	15.000	10.000
100	34	25.000	15.000	10.000
100	35	5.000	5.000	0.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	20.000	15.000	5.000
100	39	15.000	5.000	10.000
100	41	20.000	15.000	5.000
100	42	5.000	10.000	-5.000
100	43	5.000	5.000	0.000
100	44	20.000	10.000	10.000
	Max	30.000	25.000	15.000
	Average	13.243	10.676	2.568
	Min	5.000	5.000	-15.000
	Std Dev	8.516	5.548	7.132

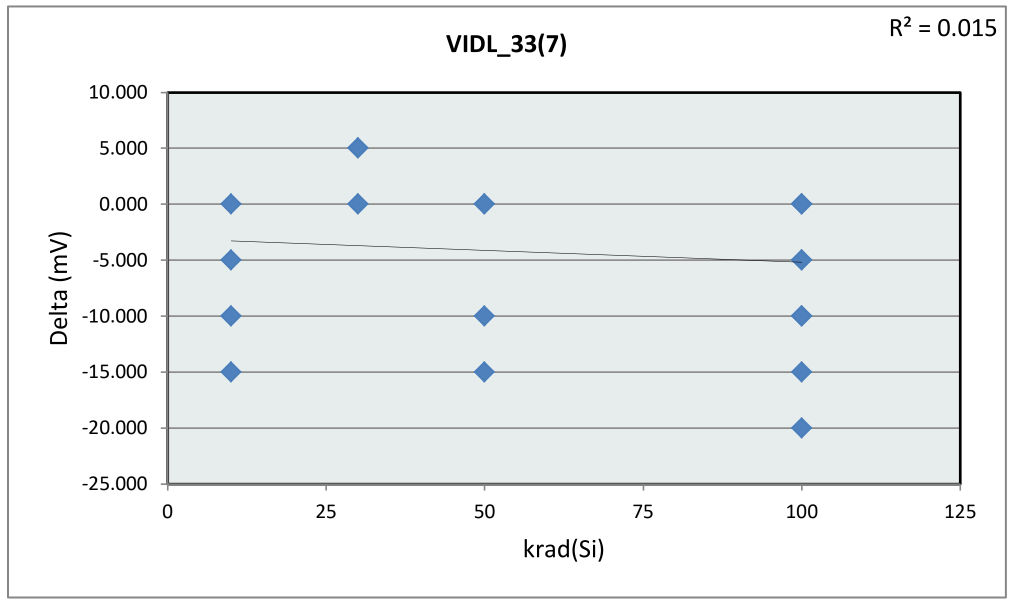


	VIDH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	10.000	10.000	12.000	10.682
Max	20.000	15.000	25.000	20.000
UL	100.000	100.000	100.000	100.000

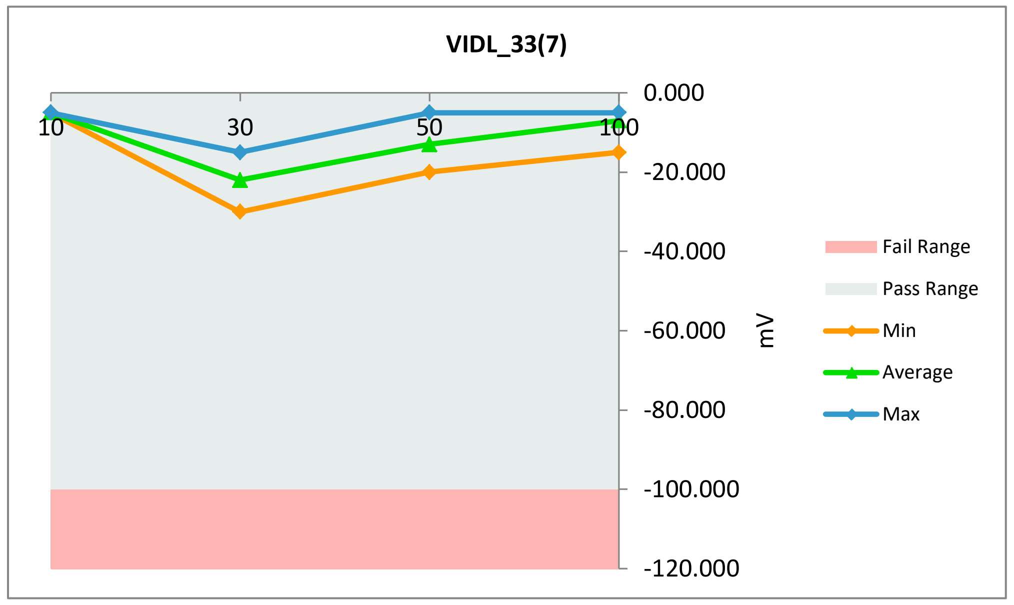


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-15.000	-5.000	-10.000
10	2	-20.000	-5.000	-15.000
10	3	-15.000	-5.000	-10.000
10	4	-10.000	-5.000	-5.000
10	5	-5.000	-5.000	0.000
30	1	-25.000	-30.000	5.000
30	2	-10.000	-15.000	5.000
30	3	-25.000	-30.000	5.000
30	4	-15.000	-15.000	0.000
30	5	-20.000	-20.000	0.000
50	11	-15.000	-15.000	0.000
50	12	-20.000	-5.000	-15.000
50	13	-20.000	-20.000	0.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-20.000	-10.000
100	22	-15.000	-5.000	-10.000
100	23	-10.000	-5.000	-5.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-5.000	-10.000
100	26	-5.000	-5.000	0.000
100	27	-35.000	-15.000	-20.000
100	28	-30.000	-15.000	-15.000
100	29	-5.000	-5.000	0.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-10.000	-10.000
100	32	-10.000	-5.000	-5.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-10.000	-10.000
100	36	-25.000	-15.000	-10.000
100	37	-20.000	-10.000	-10.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	41	-5.000	-5.000	0.000
100	42	-10.000	-5.000	-5.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-14.189	-9.595	-4.595
	Min	-35.000	-30.000	-20.000
	Std Dev	8.540	7.108	6.388

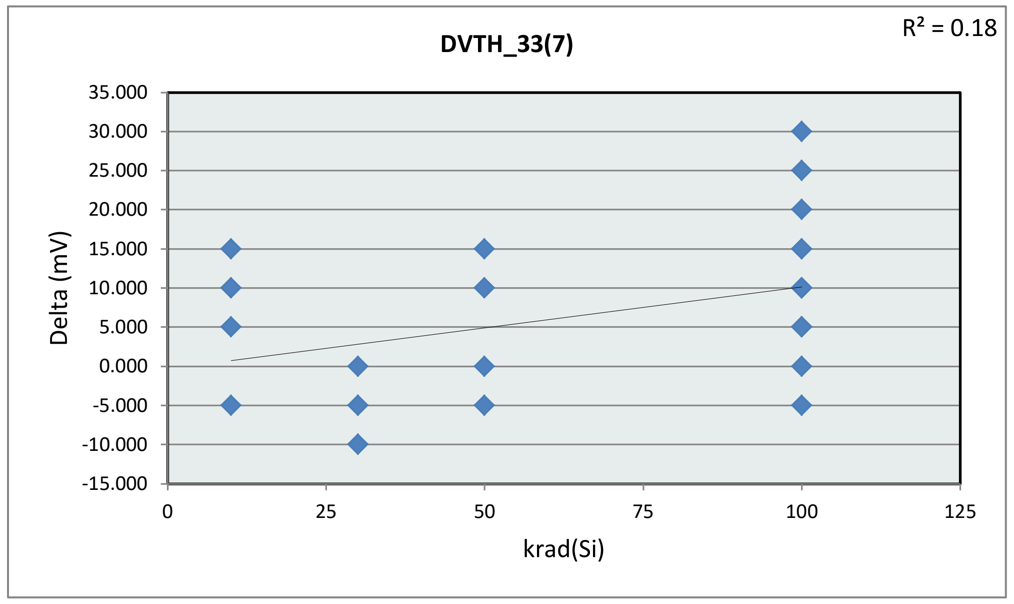


	VIDL_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-20.000	-15.000
Average	-5.000	-22.000	-13.000	-7.045
Max	-5.000	-15.000	-5.000	-5.000
UL				

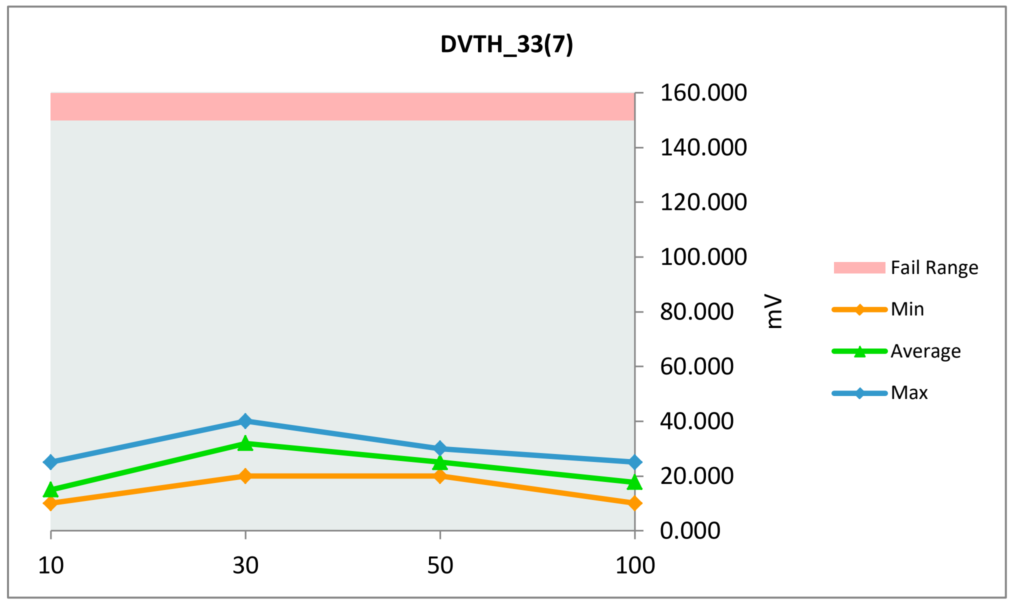


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		150	150	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	35.000	25.000	10.000
10	2	25.000	10.000	15.000
10	3	25.000	15.000	10.000
10	4	15.000	10.000	5.000
10	5	10.000	15.000	-5.000
30	1	30.000	35.000	-5.000
30	2	15.000	20.000	-5.000
30	3	30.000	40.000	-10.000
30	4	30.000	30.000	0.000
30	5	25.000	35.000	-10.000
50	11	35.000	20.000	15.000
50	12	25.000	25.000	0.000
50	13	35.000	25.000	10.000
50	14	25.000	30.000	-5.000
50	15	35.000	25.000	10.000
100	22	20.000	10.000	10.000
100	23	35.000	20.000	15.000
100	24	25.000	15.000	10.000
100	25	45.000	20.000	25.000
100	26	35.000	25.000	10.000
100	27	55.000	25.000	30.000
100	28	35.000	20.000	15.000
100	29	20.000	15.000	5.000
100	30	25.000	20.000	5.000
100	31	25.000	15.000	10.000
100	32	15.000	20.000	-5.000
100	33	30.000	20.000	10.000
100	34	30.000	20.000	10.000
100	35	25.000	15.000	10.000
100	36	30.000	20.000	10.000
100	37	40.000	20.000	20.000
100	38	25.000	20.000	5.000
100	39	20.000	10.000	10.000
100	41	25.000	20.000	5.000
100	42	15.000	15.000	0.000
100	43	20.000	10.000	10.000
100	44	25.000	15.000	10.000
	Max	55.000	40.000	30.000
	Average	27.432	20.270	7.162
	Min	10.000	10.000	-10.000
	Std Dev	8.946	7.260	8.940



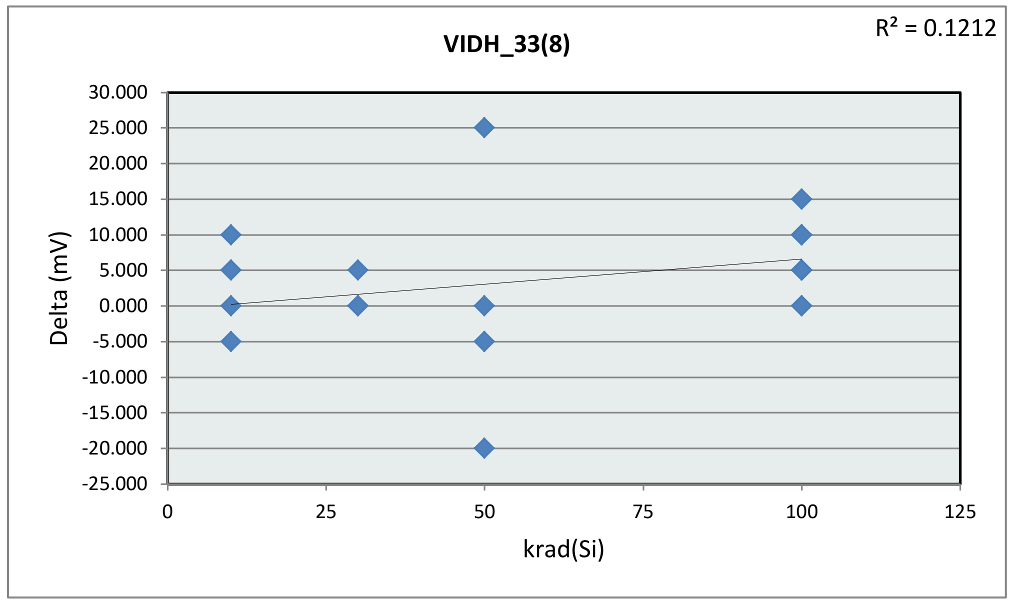
	DVTH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	20.000	10.000
Average	15.000	32.000	25.000	17.727
Max	25.000	40.000	30.000	25.000
UL	150.000	150.000	150.000	150.000



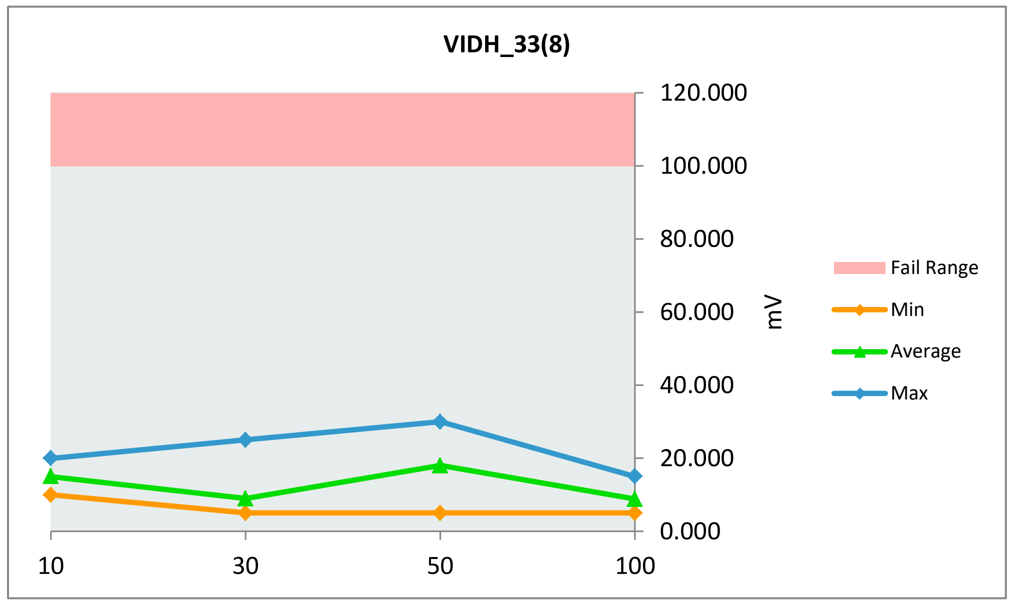
HDR Biased TID Report
SN55LVCP22A-SP

	VIDH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	10.000	10.000
10	2	15.000	15.000	0.000
10	3	15.000	10.000	5.000
10	4	25.000	20.000	5.000
10	5	15.000	20.000	-5.000
30	1	10.000	5.000	5.000
30	2	25.000	25.000	0.000
30	3	5.000	5.000	0.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	30.000	5.000	25.000
50	12	25.000	30.000	-5.000
50	13	5.000	25.000	-20.000
50	14	20.000	20.000	0.000
50	15	5.000	10.000	-5.000
100	22	15.000	10.000	5.000
100	23	20.000	10.000	10.000
100	24	15.000	5.000	10.000
100	25	5.000	5.000	0.000
100	26	15.000	10.000	5.000
100	27	25.000	10.000	15.000
100	28	15.000	5.000	10.000
100	29	15.000	10.000	5.000
100	30	20.000	10.000	10.000
100	31	15.000	10.000	5.000
100	32	20.000	10.000	10.000
100	33	20.000	15.000	5.000
100	34	20.000	10.000	10.000
100	35	25.000	10.000	15.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	10.000	5.000	5.000
100	39	15.000	10.000	5.000
100	41	10.000	5.000	5.000
100	42	15.000	10.000	5.000
100	43	5.000	5.000	0.000
100	44	25.000	15.000	10.000
	Max	30.000	30.000	25.000
	Average	15.541	10.946	4.595
	Min	5.000	5.000	-20.000
	Std Dev	7.244	6.438	7.395

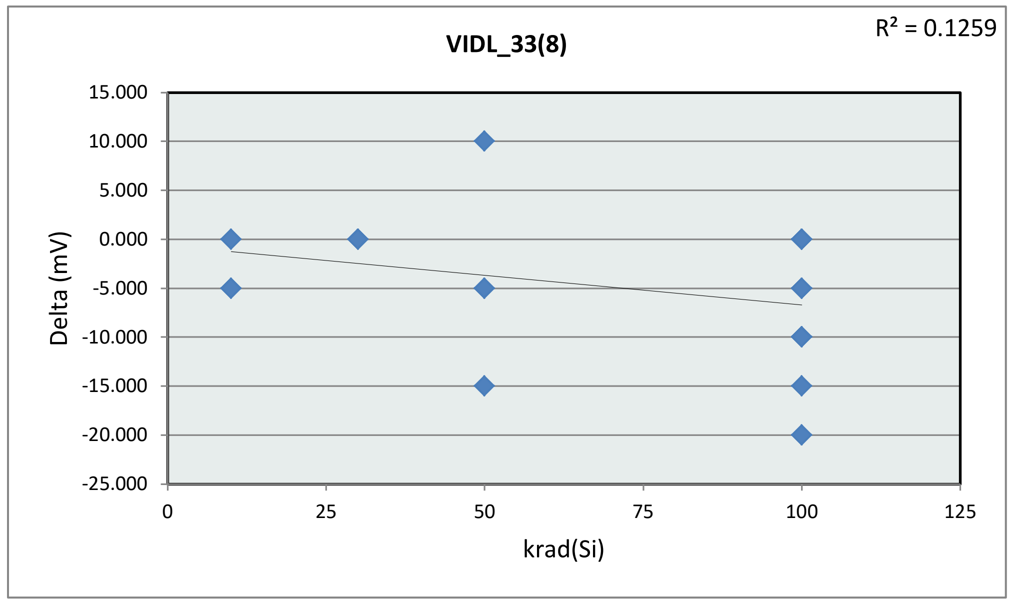


	VIDH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	15.000	9.000	18.000	8.864
Max	20.000	25.000	30.000	15.000
UL	100.000	100.000	100.000	100.000

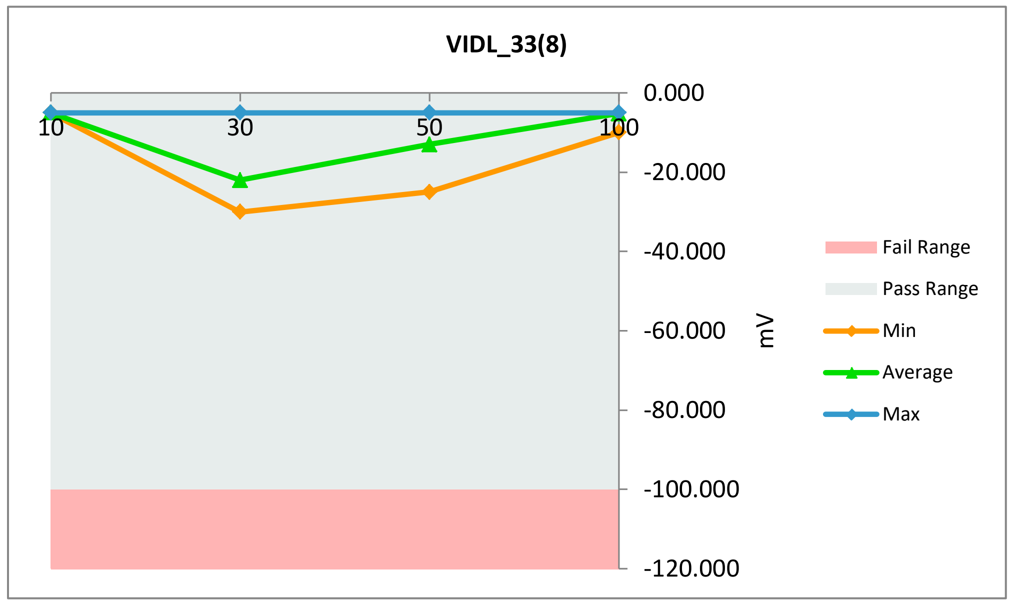


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_33(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	-10.000	-5.000	-5.000
10	2	-10.000	-5.000	-5.000
10	3	-10.000	-5.000	-5.000
10	4	-5.000	-5.000	0.000
10	5	-5.000	-5.000	0.000
30	1	-20.000	-20.000	0.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-30.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-25.000	-10.000	-15.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-25.000	-5.000
100	22	-10.000	-5.000	-5.000
100	23	-15.000	-5.000	-10.000
100	24	-10.000	-5.000	-5.000
100	25	-25.000	-5.000	-20.000
100	26	-10.000	-5.000	-5.000
100	27	-25.000	-5.000	-20.000
100	28	-20.000	-10.000	-10.000
100	29	-5.000	-5.000	0.000
100	30	-5.000	-5.000	0.000
100	31	-10.000	-5.000	-5.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-15.000	-5.000	-10.000
100	35	-10.000	-5.000	-5.000
100	36	-20.000	-5.000	-15.000
100	37	-15.000	-5.000	-10.000
100	38	-15.000	-5.000	-10.000
100	39	-5.000	-5.000	0.000
100	41	-15.000	-5.000	-10.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-13.514	-8.514	-5.000
	Min	-30.000	-30.000	-20.000
	Std Dev	8.068	7.625	6.236

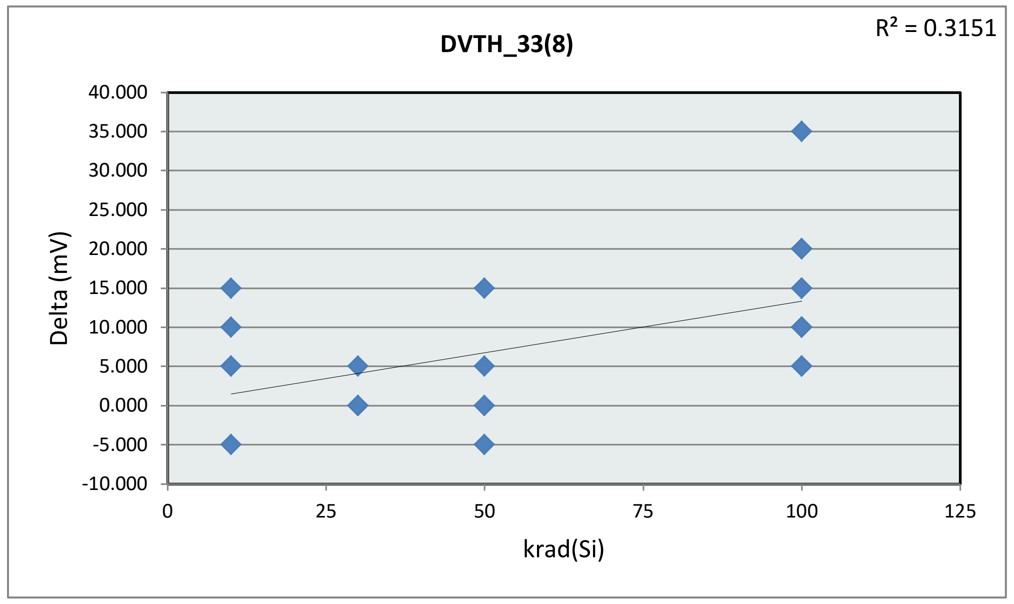


	VIDL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-25.000	-10.000
Average	-5.000	-22.000	-13.000	-5.227
Max	-5.000	-5.000	-5.000	-5.000
UL				

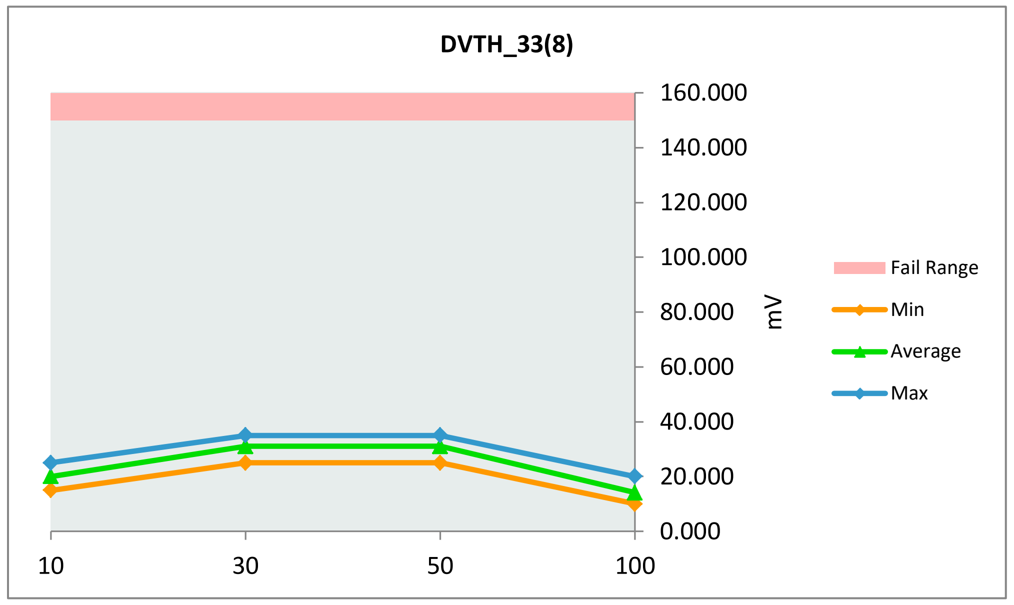


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	30.000	15.000	15.000
10	2	25.000	20.000	5.000
10	3	25.000	15.000	10.000
10	4	30.000	25.000	5.000
10	5	20.000	25.000	-5.000
30	1	30.000	25.000	5.000
30	2	30.000	30.000	0.000
30	3	35.000	35.000	0.000
30	4	30.000	30.000	0.000
30	5	35.000	35.000	0.000
50	11	40.000	25.000	15.000
50	12	35.000	35.000	0.000
50	13	30.000	35.000	-5.000
50	14	30.000	25.000	5.000
50	15	35.000	35.000	0.000
100	22	25.000	15.000	10.000
100	23	35.000	15.000	20.000
100	24	25.000	10.000	15.000
100	25	30.000	10.000	20.000
100	26	25.000	15.000	10.000
100	27	50.000	15.000	35.000
100	28	35.000	15.000	20.000
100	29	20.000	15.000	5.000
100	30	25.000	15.000	10.000
100	31	25.000	15.000	10.000
100	32	25.000	15.000	10.000
100	33	25.000	20.000	5.000
100	34	35.000	15.000	20.000
100	35	35.000	15.000	20.000
100	36	25.000	10.000	15.000
100	37	35.000	15.000	20.000
100	38	25.000	10.000	15.000
100	39	20.000	15.000	5.000
100	41	25.000	10.000	15.000
100	42	20.000	15.000	5.000
100	43	20.000	10.000	10.000
100	44	30.000	20.000	10.000
	Max	50.000	35.000	35.000
	Average	29.054	19.459	9.595
	Min	20.000	10.000	-5.000
	Std Dev	6.438	8.231	8.529

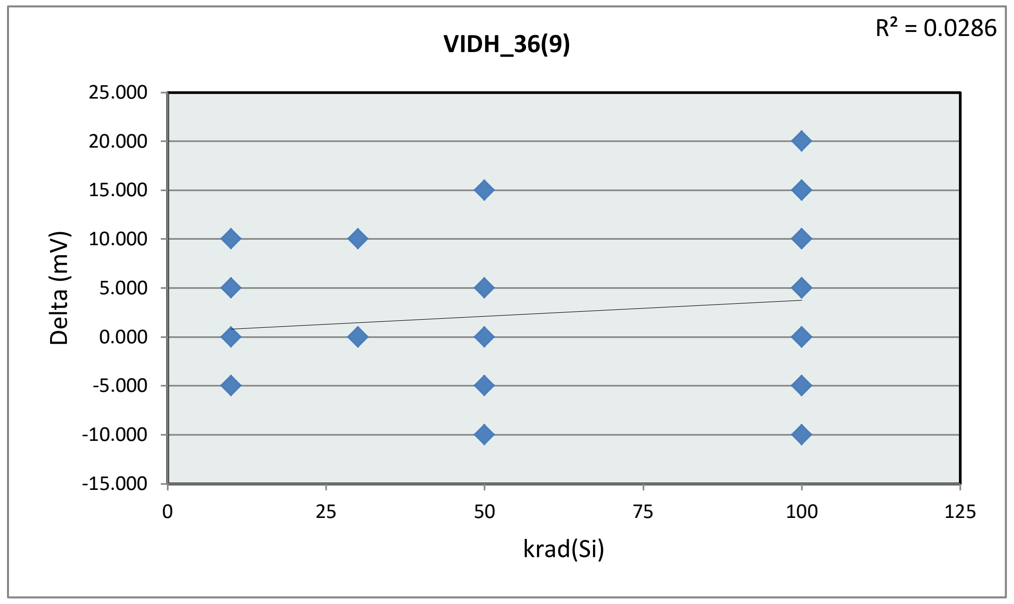


	DVTH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	25.000	10.000
Average	20.000	31.000	31.000	14.091
Max	25.000	35.000	35.000	20.000
UL	150.000	150.000	150.000	150.000

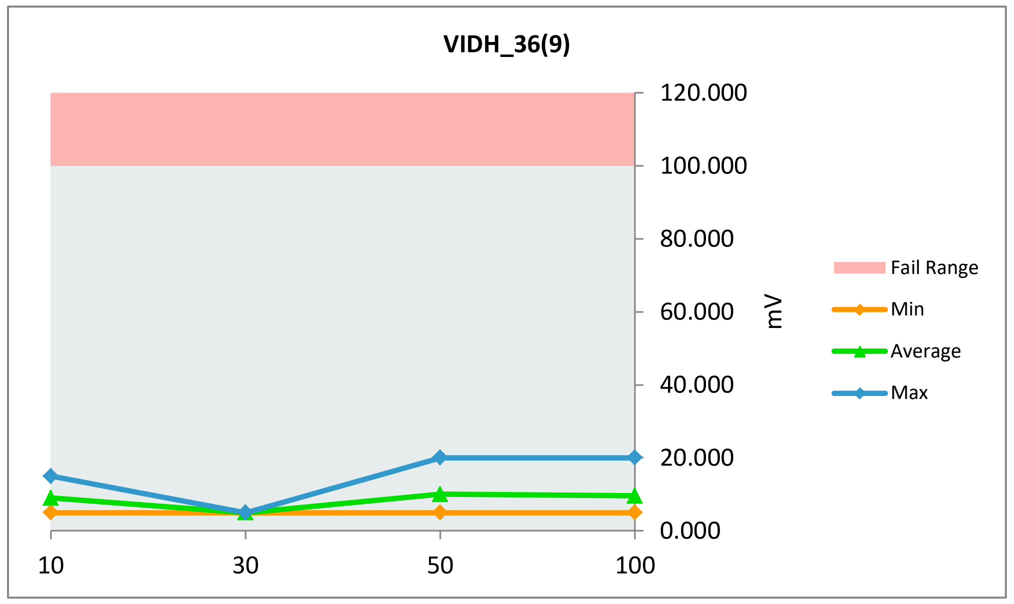


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	15.000	5.000
10	2	5.000	5.000	0.000
10	3	5.000	10.000	-5.000
10	4	5.000	10.000	-5.000
10	5	15.000	5.000	10.000
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	5.000	0.000
30	4	15.000	5.000	10.000
30	5	5.000	5.000	0.000
50	11	20.000	5.000	15.000
50	12	5.000	15.000	-10.000
50	13	10.000	5.000	5.000
50	14	15.000	20.000	-5.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	20.000	10.000	10.000
100	24	5.000	10.000	-5.000
100	25	30.000	10.000	20.000
100	26	30.000	20.000	10.000
100	27	15.000	10.000	5.000
100	28	5.000	5.000	0.000
100	29	15.000	10.000	5.000
100	30	5.000	15.000	-10.000
100	31	5.000	5.000	0.000
100	32	15.000	10.000	5.000
100	33	20.000	15.000	5.000
100	34	25.000	10.000	15.000
100	35	5.000	5.000	0.000
100	36	5.000	5.000	0.000
100	37	5.000	10.000	-5.000
100	38	20.000	15.000	5.000
100	39	5.000	10.000	-5.000
100	41	20.000	15.000	5.000
100	42	15.000	5.000	10.000
100	43	5.000	5.000	0.000
100	44	20.000	5.000	15.000
	Max	30.000	20.000	20.000
	Average	11.757	8.919	2.838
	Min	5.000	5.000	-10.000
	Std Dev	7.925	4.585	7.124

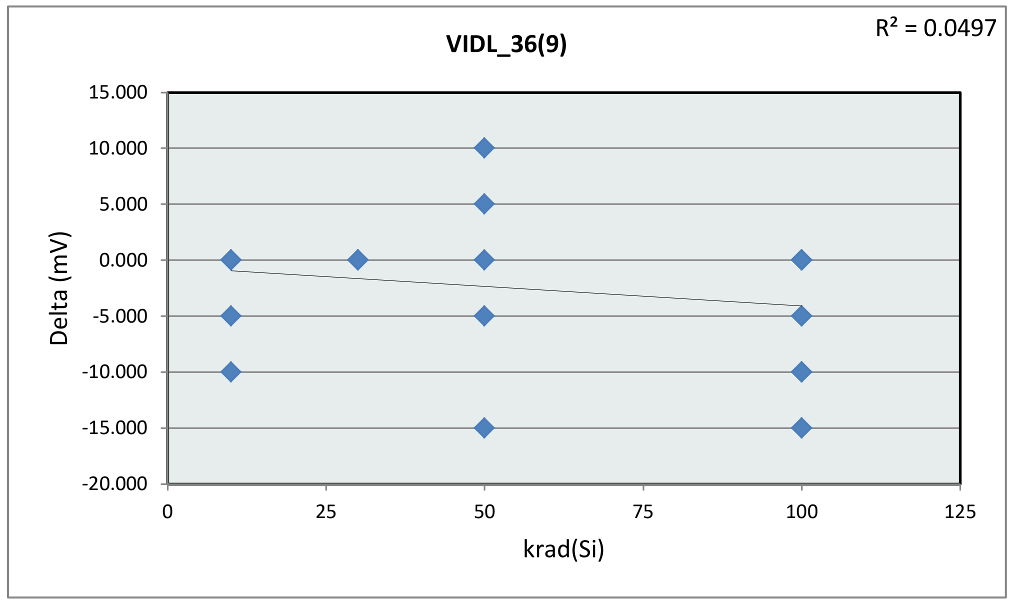


	VIDH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	9.000	5.000	10.000	9.545
Max	15.000	5.000	20.000	20.000
UL	100.000	100.000	100.000	100.000

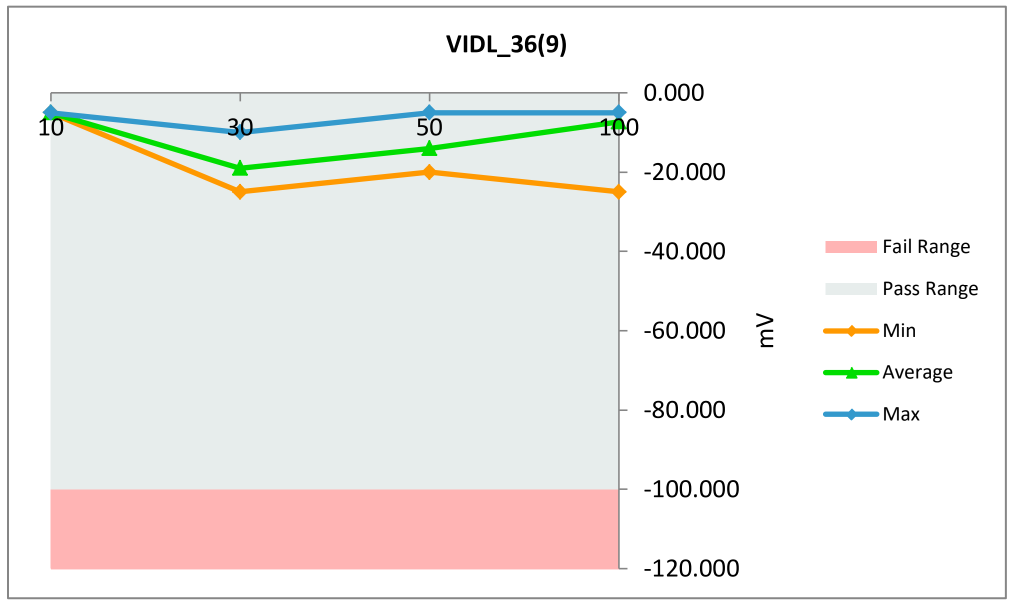


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-10.000	-5.000	-5.000
10	2	-15.000	-5.000	-10.000
10	3	-5.000	-5.000	0.000
10	4	-5.000	-5.000	0.000
10	5	-5.000	-5.000	0.000
30	1	-25.000	-25.000	0.000
30	2	-10.000	-10.000	0.000
30	3	-25.000	-25.000	0.000
30	4	-15.000	-15.000	0.000
30	5	-20.000	-20.000	0.000
50	11	-5.000	-15.000	10.000
50	12	-20.000	-15.000	-5.000
50	13	-15.000	-20.000	5.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-15.000	-15.000
100	22	-10.000	-5.000	-5.000
100	23	-5.000	-5.000	0.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-5.000	-10.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-25.000	-5.000
100	28	-30.000	-15.000	-15.000
100	29	-5.000	-5.000	0.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-10.000	-10.000
100	32	-10.000	-5.000	-5.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-10.000	-10.000
100	36	-25.000	-10.000	-15.000
100	37	-20.000	-10.000	-10.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	41	-5.000	-5.000	0.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-12.568	-9.459	-3.108
	Min	-30.000	-25.000	-15.000
	Std Dev	8.630	6.539	5.695

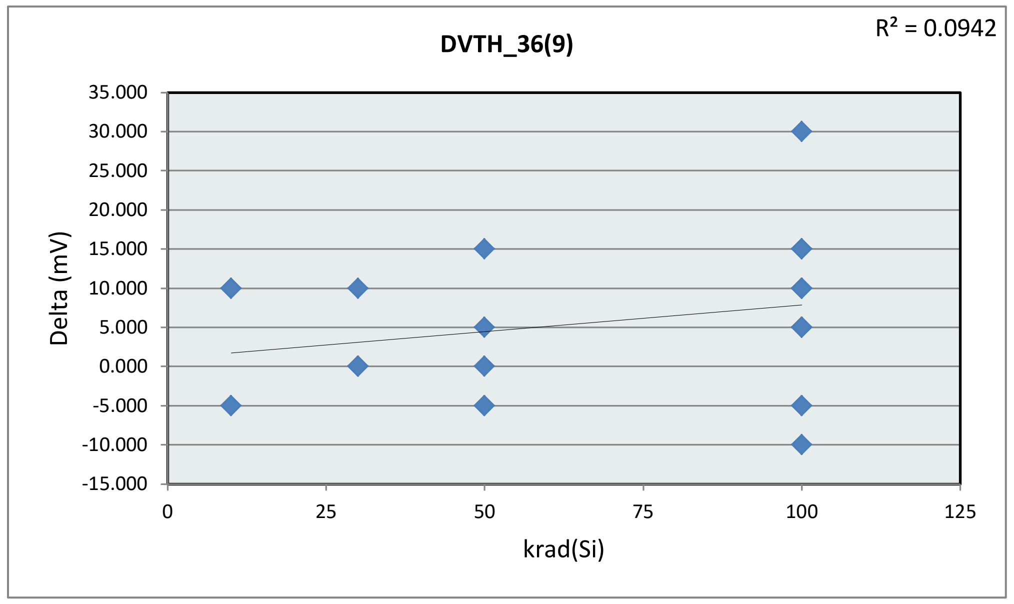


	VIDL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-25.000	-20.000	-25.000
Average	-5.000	-19.000	-14.000	-7.273
Max	-5.000	-10.000	-5.000	-5.000
UL				

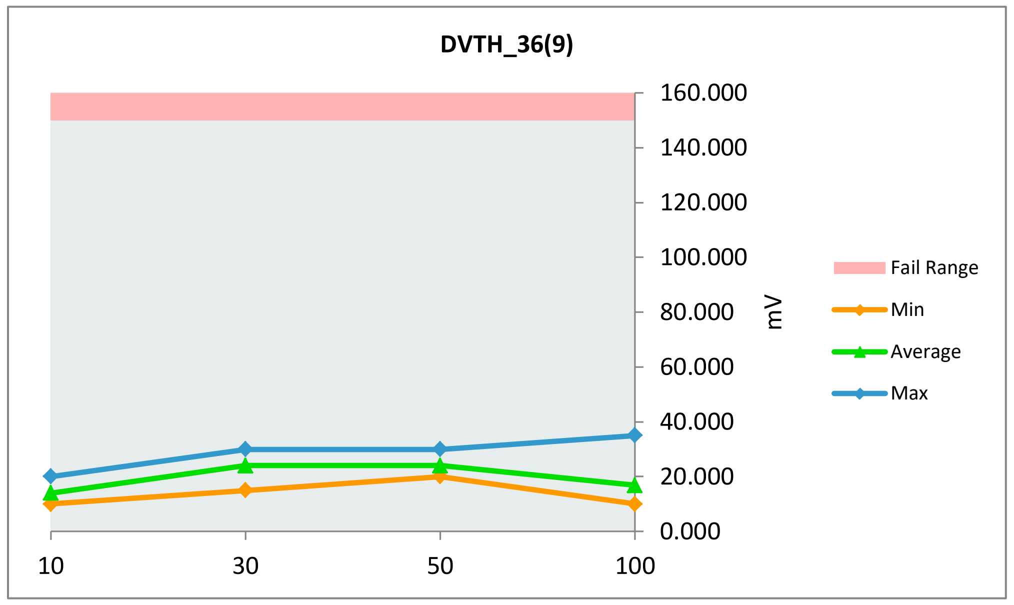


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	30.000	20.000	10.000
10	2	20.000	10.000	10.000
10	3	10.000	15.000	-5.000
10	4	10.000	15.000	-5.000
10	5	20.000	10.000	10.000
30	1	30.000	30.000	0.000
30	2	15.000	15.000	0.000
30	3	30.000	30.000	0.000
30	4	30.000	20.000	10.000
30	5	25.000	25.000	0.000
50	11	25.000	20.000	5.000
50	12	25.000	30.000	-5.000
50	13	25.000	25.000	0.000
50	14	20.000	25.000	-5.000
50	15	35.000	20.000	15.000
100	22	15.000	10.000	5.000
100	23	25.000	15.000	10.000
100	24	10.000	15.000	-5.000
100	25	45.000	15.000	30.000
100	26	35.000	25.000	10.000
100	27	45.000	35.000	10.000
100	28	35.000	20.000	15.000
100	29	20.000	15.000	5.000
100	30	10.000	20.000	-10.000
100	31	25.000	15.000	10.000
100	32	25.000	15.000	10.000
100	33	25.000	20.000	5.000
100	34	30.000	15.000	15.000
100	35	25.000	15.000	10.000
100	36	30.000	15.000	15.000
100	37	25.000	20.000	5.000
100	38	25.000	20.000	5.000
100	39	10.000	15.000	-5.000
100	41	25.000	20.000	5.000
100	42	20.000	10.000	10.000
100	43	20.000	10.000	10.000
100	44	25.000	10.000	15.000
	Max	45.000	35.000	30.000
	Average	24.324	18.378	5.946
	Min	10.000	10.000	-10.000
	Std Dev	8.673	6.352	8.066

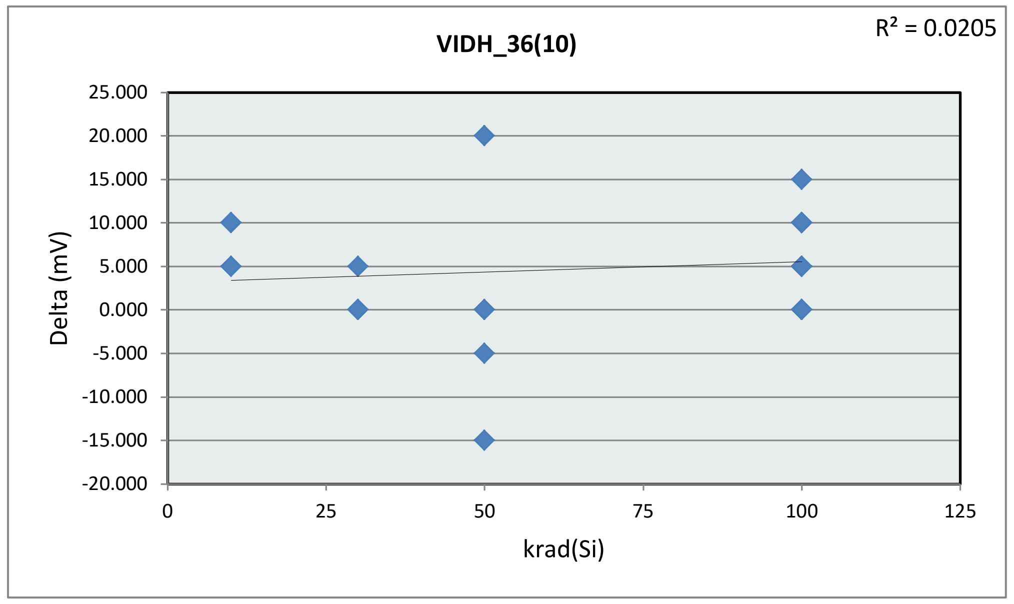


	DVTH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	15.000	20.000	10.000
Average	14.000	24.000	24.000	16.818
Max	20.000	30.000	30.000	35.000
UL	150.000	150.000	150.000	150.000

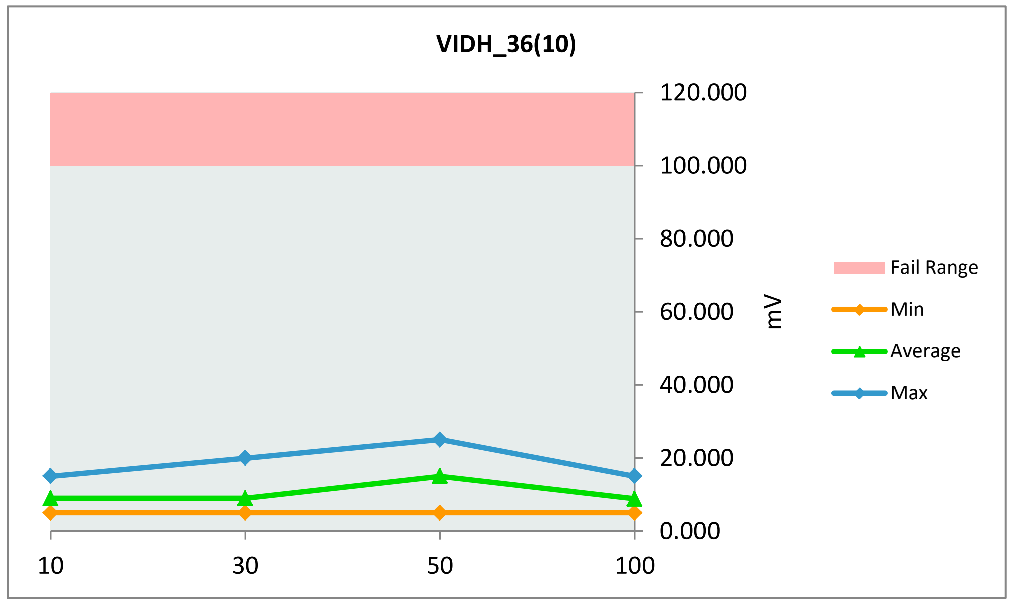


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	10.000	10.000
10	2	15.000	10.000	5.000
10	3	15.000	5.000	10.000
10	4	20.000	15.000	5.000
10	5	15.000	5.000	10.000
30	1	5.000	5.000	0.000
30	2	20.000	20.000	0.000
30	3	5.000	5.000	0.000
30	4	15.000	10.000	5.000
30	5	5.000	5.000	0.000
50	11	25.000	5.000	20.000
50	12	25.000	25.000	0.000
50	13	5.000	20.000	-15.000
50	14	15.000	20.000	-5.000
50	15	5.000	5.000	0.000
100	22	15.000	10.000	5.000
100	23	20.000	10.000	10.000
100	24	15.000	10.000	5.000
100	25	5.000	5.000	0.000
100	26	15.000	10.000	5.000
100	27	25.000	10.000	15.000
100	28	15.000	5.000	10.000
100	29	15.000	10.000	5.000
100	30	15.000	10.000	5.000
100	31	15.000	5.000	10.000
100	32	15.000	10.000	5.000
100	33	20.000	10.000	10.000
100	34	20.000	10.000	10.000
100	35	20.000	10.000	10.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	5.000	5.000	0.000
100	39	15.000	15.000	0.000
100	41	10.000	5.000	5.000
100	42	15.000	10.000	5.000
100	43	5.000	5.000	0.000
100	44	25.000	15.000	10.000
	Max	25.000	25.000	20.000
	Average	14.595	9.730	4.865
	Min	5.000	5.000	-15.000
	Std Dev	6.496	5.130	6.179

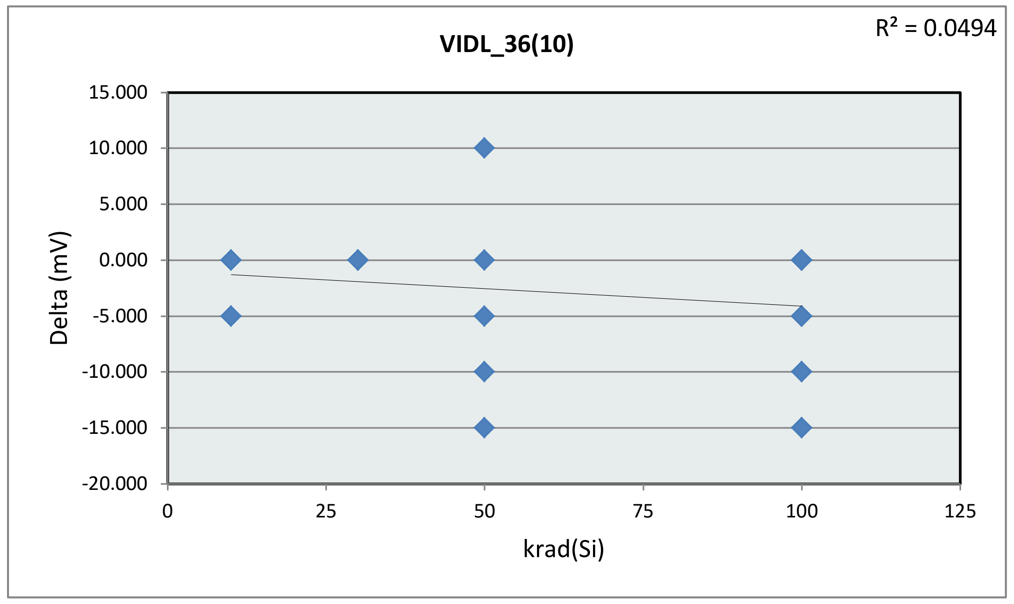


	VIDH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	9.000	9.000	15.000	8.864
Max	15.000	20.000	25.000	15.000
UL	100.000	100.000	100.000	100.000

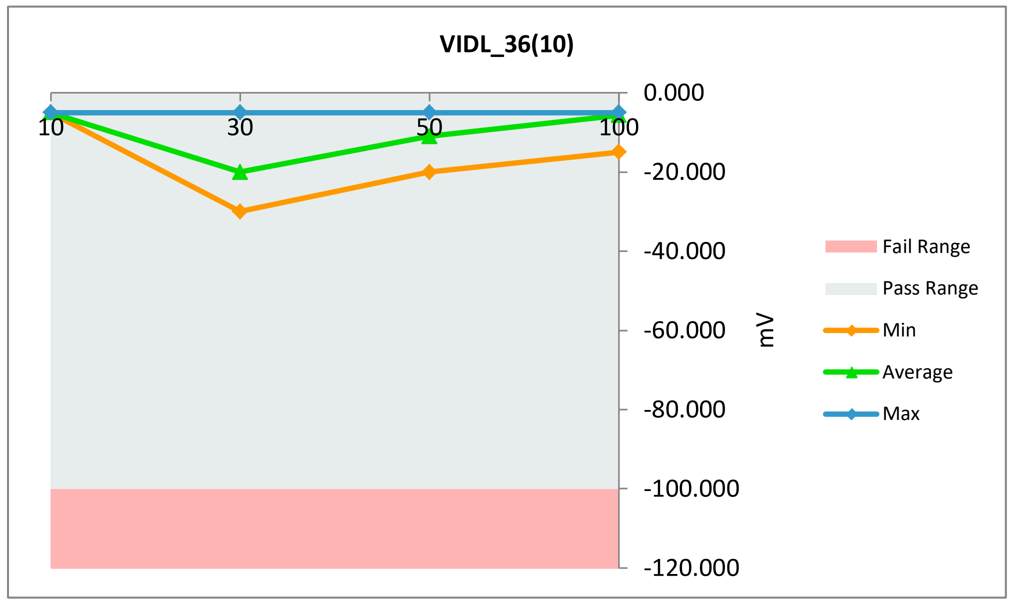


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-10.000	-5.000	-5.000
10	2	-10.000	-5.000	-5.000
10	3	-5.000	-5.000	0.000
10	4	-5.000	-5.000	0.000
10	5	-5.000	-5.000	0.000
30	1	-15.000	-15.000	0.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-25.000	-25.000	0.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-20.000	-5.000	-15.000
50	14	-5.000	-5.000	0.000
50	15	-30.000	-20.000	-10.000
100	22	-5.000	-5.000	0.000
100	23	-10.000	-5.000	-5.000
100	24	-5.000	-5.000	0.000
100	25	-20.000	-5.000	-15.000
100	26	-10.000	-5.000	-5.000
100	27	-20.000	-5.000	-15.000
100	28	-20.000	-10.000	-10.000
100	29	-5.000	-5.000	0.000
100	30	-10.000	-5.000	-5.000
100	31	-5.000	-5.000	0.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-10.000	-5.000	-5.000
100	35	-10.000	-5.000	-5.000
100	36	-15.000	-15.000	0.000
100	37	-10.000	-5.000	-5.000
100	38	-10.000	-5.000	-5.000
100	39	-5.000	-5.000	0.000
100	41	-15.000	-5.000	-10.000
100	42	-5.000	-5.000	0.000
100	43	-10.000	-5.000	-5.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-11.486	-8.243	-3.243
	Min	-30.000	-30.000	-15.000
	Std Dev	7.441	6.894	5.166



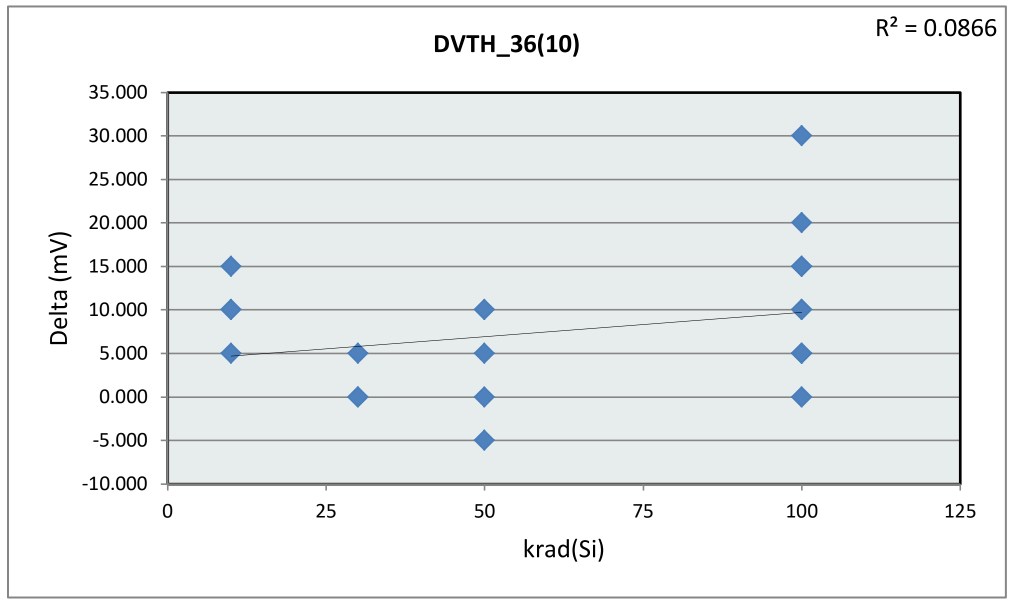
	VIDL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-20.000	-15.000
Average	-5.000	-20.000	-11.000	-5.682
Max	-5.000	-5.000	-5.000	-5.000
UL				



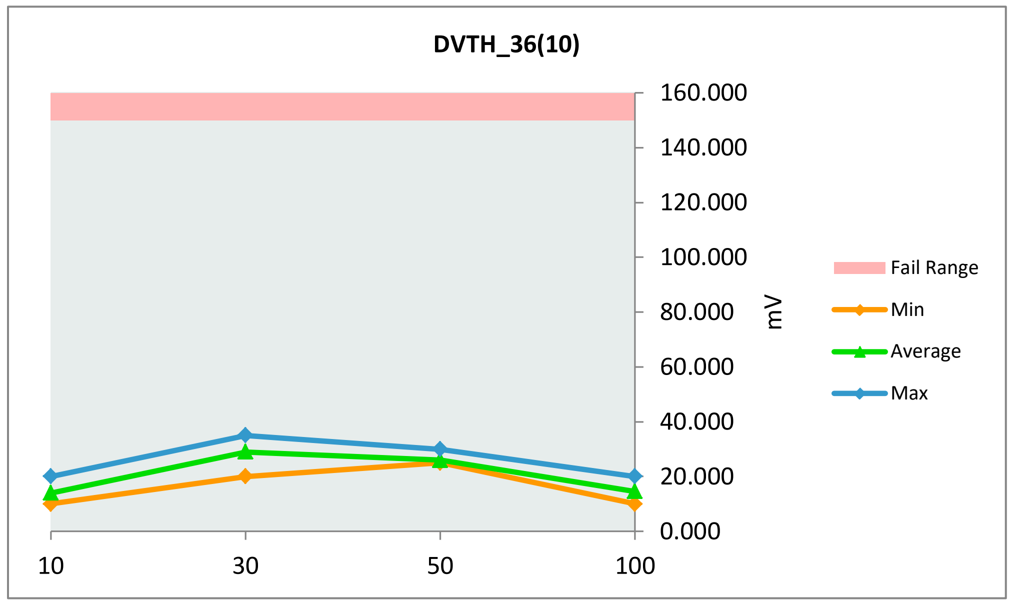
HDR Biased TID Report
SN55LVCP22A-SP

	DVTH_36(10)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	30.000	15.000	15.000
10	2	25.000	15.000	10.000
10	3	20.000	10.000	10.000
10	4	25.000	20.000	5.000
10	5	20.000	10.000	10.000
30	1	20.000	20.000	0.000
30	2	25.000	25.000	0.000
30	3	35.000	35.000	0.000
30	4	40.000	35.000	5.000
30	5	30.000	30.000	0.000
50	11	35.000	25.000	10.000
50	12	35.000	30.000	5.000
50	13	25.000	25.000	0.000
50	14	20.000	25.000	-5.000
50	15	35.000	25.000	10.000
100	22	20.000	15.000	5.000
100	23	30.000	15.000	15.000
100	24	20.000	15.000	5.000
100	25	25.000	10.000	15.000
100	26	25.000	15.000	10.000
100	27	45.000	15.000	30.000
100	28	35.000	15.000	20.000
100	29	20.000	15.000	5.000
100	30	25.000	15.000	10.000
100	31	20.000	10.000	10.000
100	32	20.000	15.000	5.000
100	33	25.000	15.000	10.000
100	34	30.000	15.000	15.000
100	35	30.000	15.000	15.000
100	36	20.000	20.000	0.000
100	37	30.000	15.000	15.000
100	38	15.000	10.000	5.000
100	39	20.000	20.000	0.000
100	41	25.000	10.000	15.000
100	42	20.000	15.000	5.000
100	43	15.000	10.000	5.000
100	44	30.000	20.000	10.000
	Max	45.000	35.000	30.000
	Average	26.081	17.973	8.108
	Min	15.000	10.000	-5.000
	Std Dev	6.986	6.918	6.907



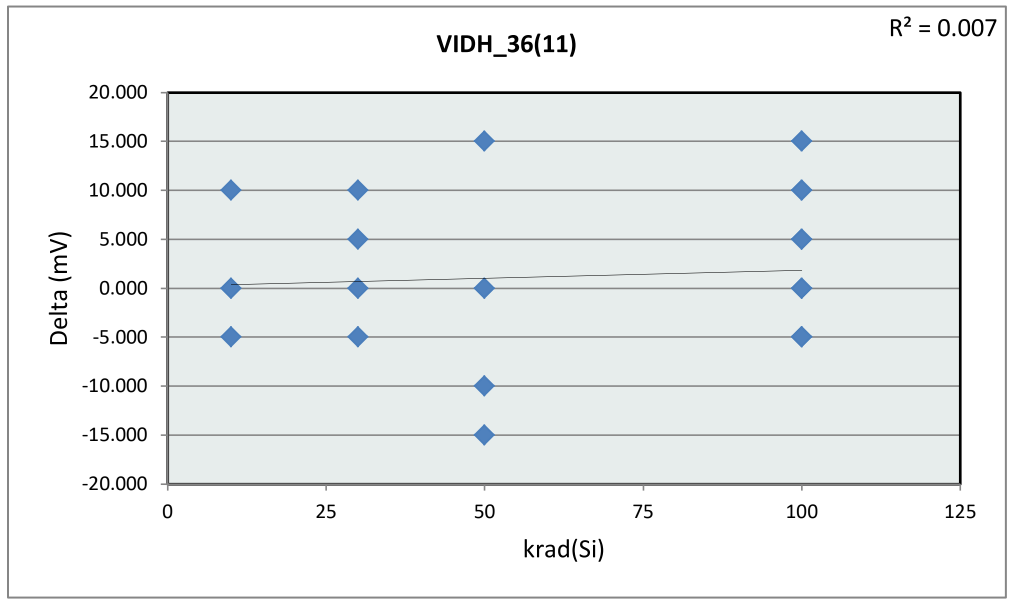
	DVTH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	25.000	10.000
Average	14.000	29.000	26.000	14.545
Max	20.000	35.000	30.000	20.000
UL	150.000	150.000	150.000	150.000



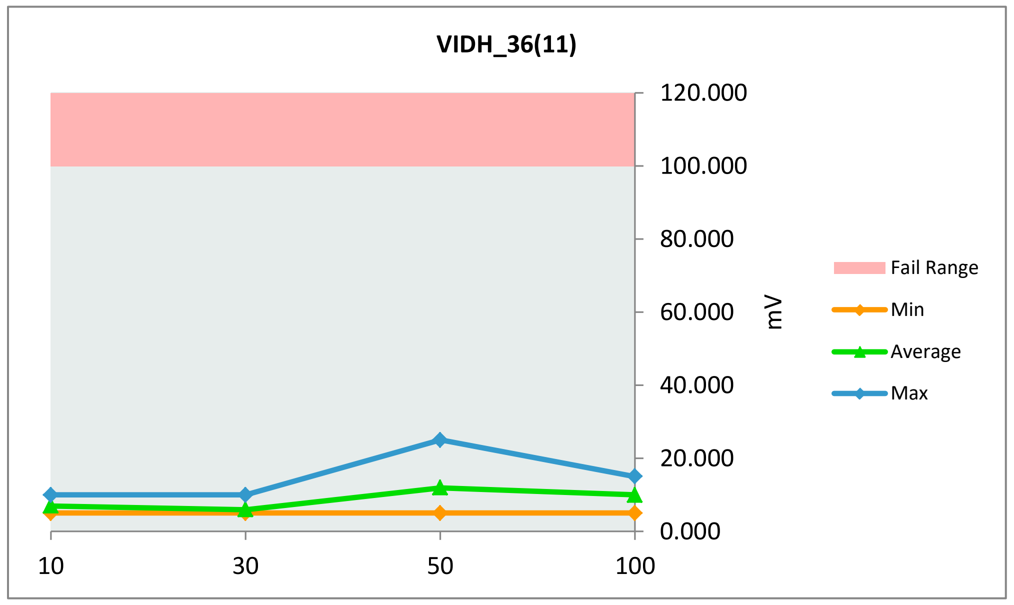
HDR Biased TID Report
SN55LVCP22A-SP

	VIDH_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	10.000	10.000
10	2	5.000	5.000	0.000
10	3	5.000	5.000	0.000
10	4	5.000	5.000	0.000
10	5	5.000	10.000	-5.000
30	1	5.000	5.000	0.000
30	2	5.000	5.000	0.000
30	3	5.000	10.000	-5.000
30	4	15.000	5.000	10.000
30	5	10.000	5.000	5.000
50	11	20.000	5.000	15.000
50	12	5.000	20.000	-15.000
50	13	5.000	5.000	0.000
50	14	15.000	25.000	-10.000
50	15	5.000	5.000	0.000
100	22	5.000	5.000	0.000
100	23	20.000	15.000	5.000
100	24	5.000	10.000	-5.000
100	25	30.000	15.000	15.000
100	26	30.000	15.000	15.000
100	27	15.000	10.000	5.000
100	28	5.000	5.000	0.000
100	29	5.000	5.000	0.000
100	30	20.000	10.000	10.000
100	31	5.000	5.000	0.000
100	32	5.000	10.000	-5.000
100	33	20.000	15.000	5.000
100	34	25.000	15.000	10.000
100	35	5.000	10.000	-5.000
100	36	5.000	5.000	0.000
100	37	5.000	10.000	-5.000
100	38	20.000	10.000	10.000
100	39	5.000	10.000	-5.000
100	41	20.000	15.000	5.000
100	42	5.000	10.000	-5.000
100	43	5.000	5.000	0.000
100	44	5.000	10.000	-5.000
	Max	30.000	25.000	15.000
	Average	10.676	9.324	1.351
	Min	5.000	5.000	-15.000
	Std Dev	8.093	4.882	7.036

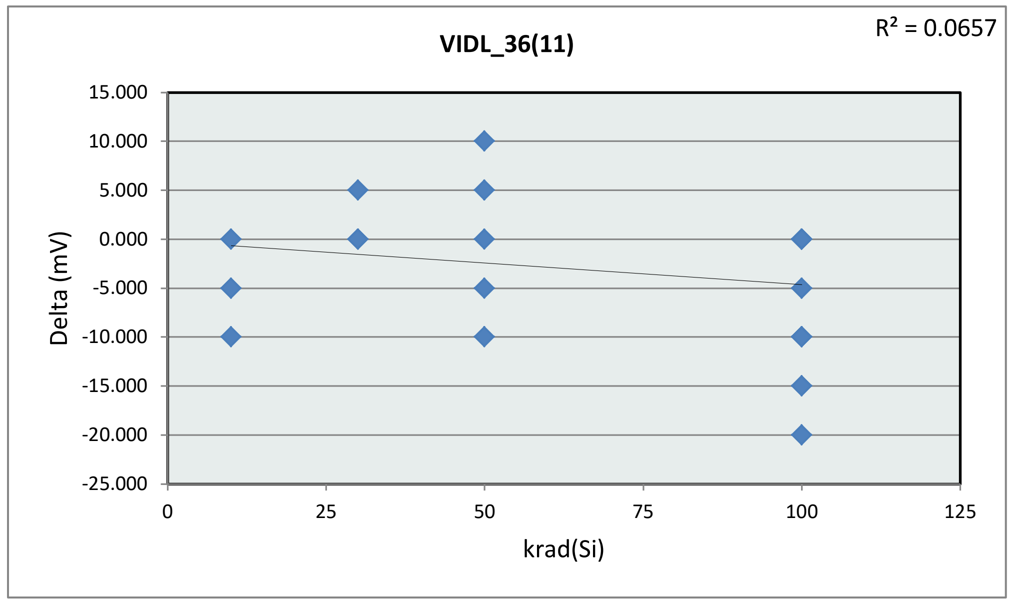


	VIDH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	7.000	6.000	12.000	10.000
Max	10.000	10.000	25.000	15.000
UL	100.000	100.000	100.000	100.000

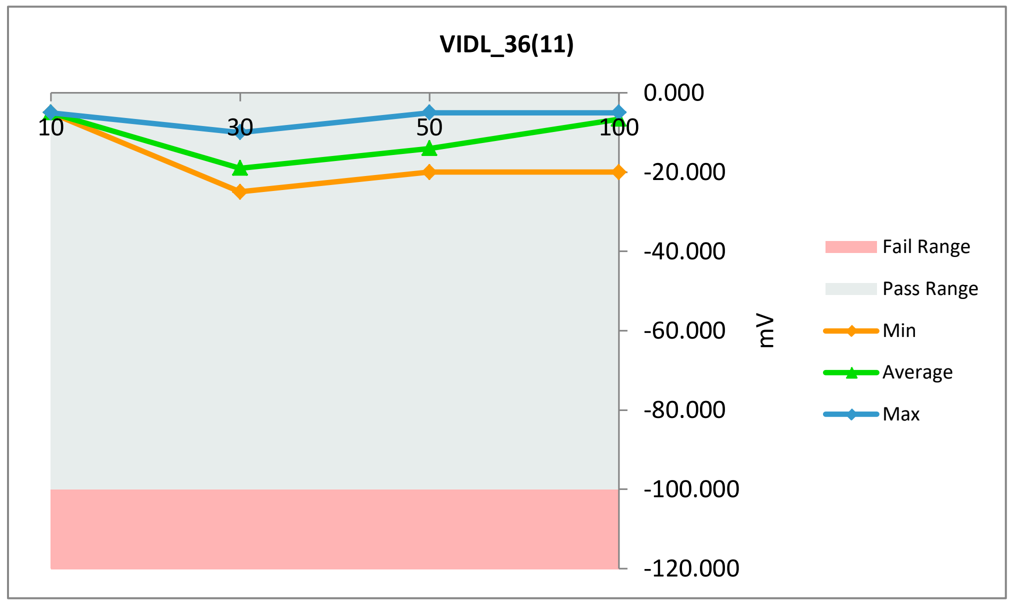


HDR Biased TID Report
SN55LVCP22A-SP

		VIDL_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	-10.000	-5.000	-5.000
10	2	-15.000	-5.000	-10.000
10	3	-5.000	-5.000	0.000
10	4	-10.000	-5.000	-5.000
10	5	-5.000	-5.000	0.000
30	1	-25.000	-25.000	0.000
30	2	-10.000	-10.000	0.000
30	3	-25.000	-25.000	0.000
30	4	-15.000	-15.000	0.000
30	5	-15.000	-20.000	5.000
50	11	-5.000	-15.000	10.000
50	12	-20.000	-15.000	-5.000
50	13	-15.000	-20.000	5.000
50	14	-5.000	-5.000	0.000
50	15	-25.000	-15.000	-10.000
100	22	-10.000	-5.000	-5.000
100	23	-5.000	-5.000	0.000
100	24	-5.000	-5.000	0.000
100	25	-15.000	-5.000	-10.000
100	26	-5.000	-5.000	0.000
100	27	-30.000	-20.000	-10.000
100	28	-30.000	-10.000	-20.000
100	29	-5.000	-5.000	0.000
100	30	-5.000	-5.000	0.000
100	31	-20.000	-10.000	-10.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-5.000	-5.000	0.000
100	35	-20.000	-5.000	-15.000
100	36	-25.000	-10.000	-15.000
100	37	-20.000	-10.000	-10.000
100	38	-5.000	-5.000	0.000
100	39	-5.000	-5.000	0.000
100	41	-5.000	-5.000	0.000
100	42	-10.000	-5.000	-5.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-12.432	-9.054	-3.378
	Min	-30.000	-25.000	-20.000
	Std Dev	8.218	6.218	6.242

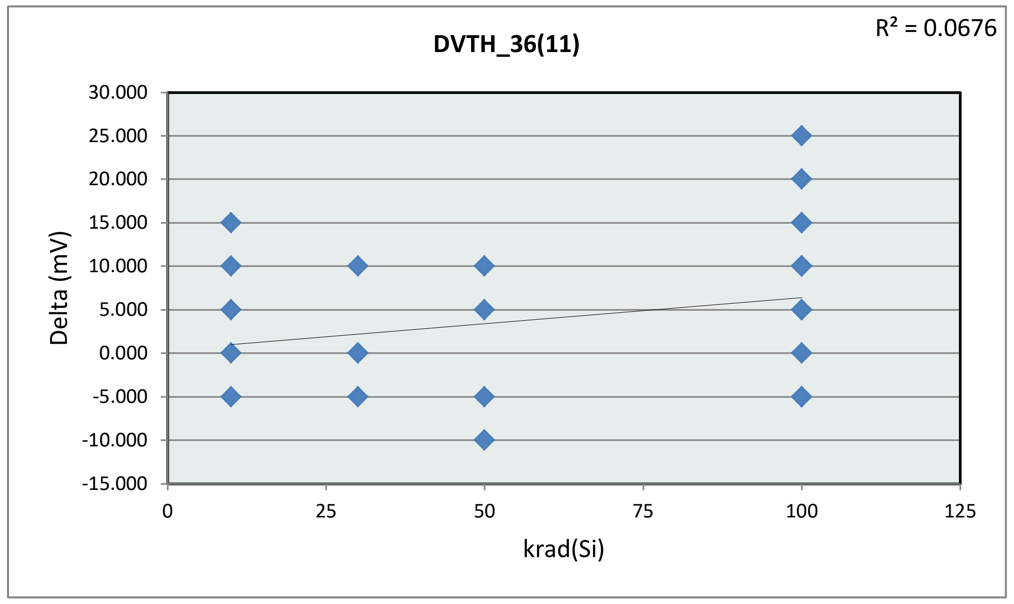


	VIDL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-25.000	-20.000	-20.000
Average	-5.000	-19.000	-14.000	-6.591
Max	-5.000	-10.000	-5.000	-5.000
UL				

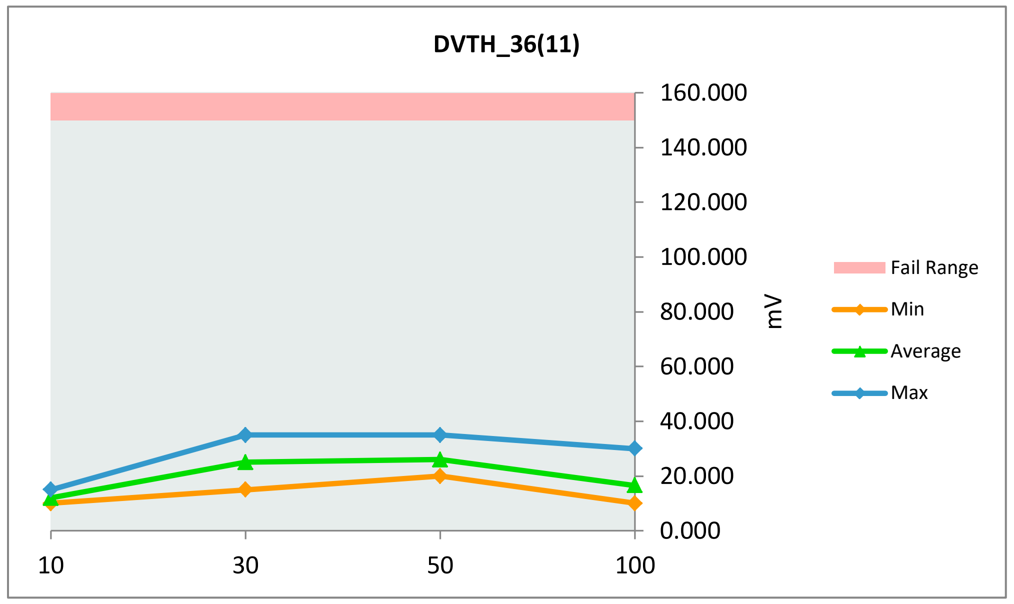


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	30.000	15.000	15.000
10	2	20.000	10.000	10.000
10	3	10.000	10.000	0.000
10	4	15.000	10.000	5.000
10	5	10.000	15.000	-5.000
30	1	30.000	30.000	0.000
30	2	15.000	15.000	0.000
30	3	30.000	35.000	-5.000
30	4	30.000	20.000	10.000
30	5	25.000	25.000	0.000
50	11	25.000	20.000	5.000
50	12	25.000	35.000	-10.000
50	13	20.000	25.000	-5.000
50	14	20.000	30.000	-10.000
50	15	30.000	20.000	10.000
100	22	15.000	10.000	5.000
100	23	25.000	20.000	5.000
100	24	10.000	15.000	-5.000
100	25	45.000	20.000	25.000
100	26	35.000	20.000	15.000
100	27	45.000	30.000	15.000
100	28	35.000	15.000	20.000
100	29	10.000	10.000	0.000
100	30	25.000	15.000	10.000
100	31	25.000	15.000	10.000
100	32	10.000	15.000	-5.000
100	33	25.000	20.000	5.000
100	34	30.000	20.000	10.000
100	35	25.000	15.000	10.000
100	36	30.000	15.000	15.000
100	37	25.000	20.000	5.000
100	38	25.000	15.000	10.000
100	39	10.000	15.000	-5.000
100	41	25.000	20.000	5.000
100	42	15.000	15.000	0.000
100	43	20.000	10.000	10.000
100	44	10.000	15.000	-5.000
	Max	45.000	35.000	25.000
	Average	23.108	18.378	4.730
	Min	10.000	10.000	-10.000
	Std Dev	9.306	6.776	8.412

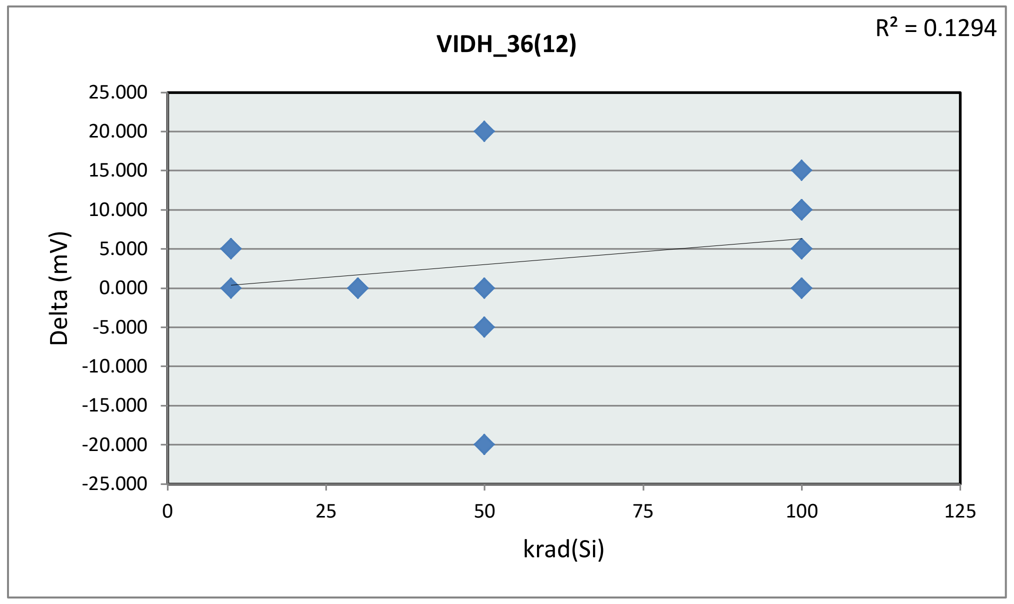


	DVTH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	15.000	20.000	10.000
Average	12.000	25.000	26.000	16.591
Max	15.000	35.000	35.000	30.000
UL	150.000	150.000	150.000	150.000

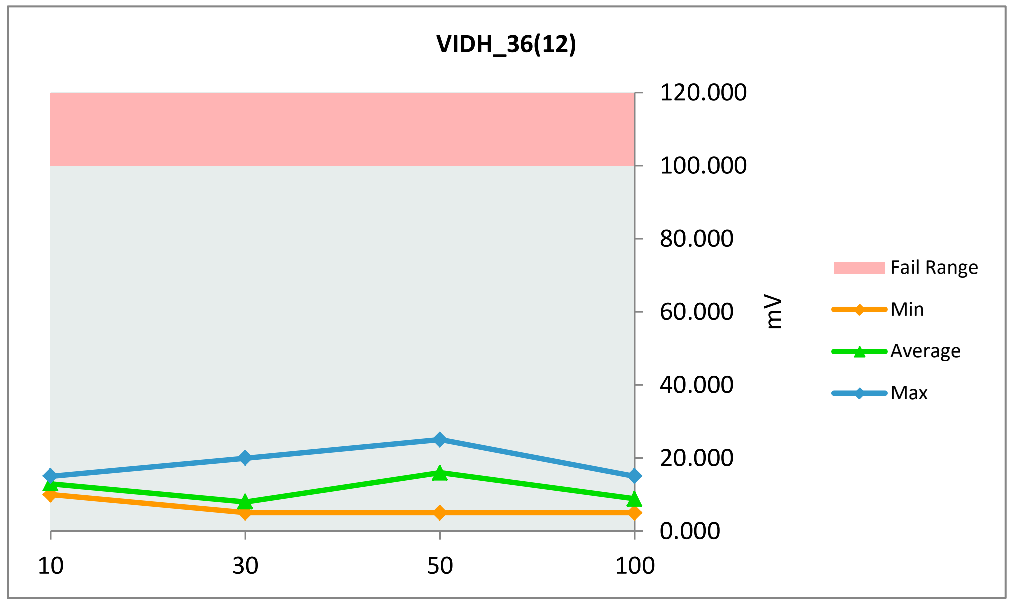


HDR Biased TID Report
SN55LVCP22A-SP

		VIDH_36(12)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	20.000	15.000	5.000
10	2	15.000	15.000	0.000
10	3	15.000	10.000	5.000
10	4	20.000	15.000	5.000
10	5	15.000	10.000	5.000
30	1	5.000	5.000	0.000
30	2	20.000	20.000	0.000
30	3	5.000	5.000	0.000
30	4	5.000	5.000	0.000
30	5	5.000	5.000	0.000
50	11	25.000	5.000	20.000
50	12	25.000	25.000	0.000
50	13	5.000	25.000	-20.000
50	14	15.000	20.000	-5.000
50	15	5.000	5.000	0.000
100	22	10.000	10.000	0.000
100	23	20.000	10.000	10.000
100	24	10.000	10.000	0.000
100	25	20.000	5.000	15.000
100	26	15.000	10.000	5.000
100	27	20.000	10.000	10.000
100	28	15.000	5.000	10.000
100	29	15.000	10.000	5.000
100	30	15.000	10.000	5.000
100	31	15.000	10.000	5.000
100	32	20.000	10.000	10.000
100	33	20.000	10.000	10.000
100	34	20.000	10.000	10.000
100	35	20.000	10.000	10.000
100	36	5.000	5.000	0.000
100	37	20.000	10.000	10.000
100	38	10.000	5.000	5.000
100	39	20.000	10.000	10.000
100	41	10.000	5.000	5.000
100	42	15.000	10.000	5.000
100	43	5.000	5.000	0.000
100	44	25.000	15.000	10.000
	Max	25.000	25.000	20.000
	Average	14.730	10.270	4.459
	Min	5.000	5.000	-20.000
	Std Dev	6.449	5.394	6.644



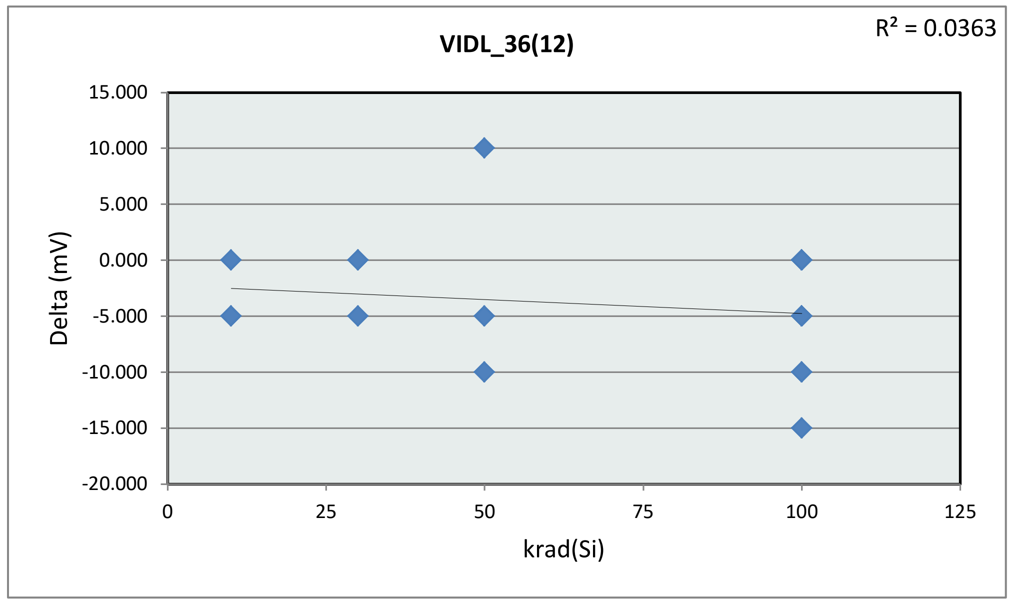
	VIDH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	13.000	8.000	16.000	8.864
Max	15.000	20.000	25.000	15.000
UL	100.000	100.000	100.000	100.000



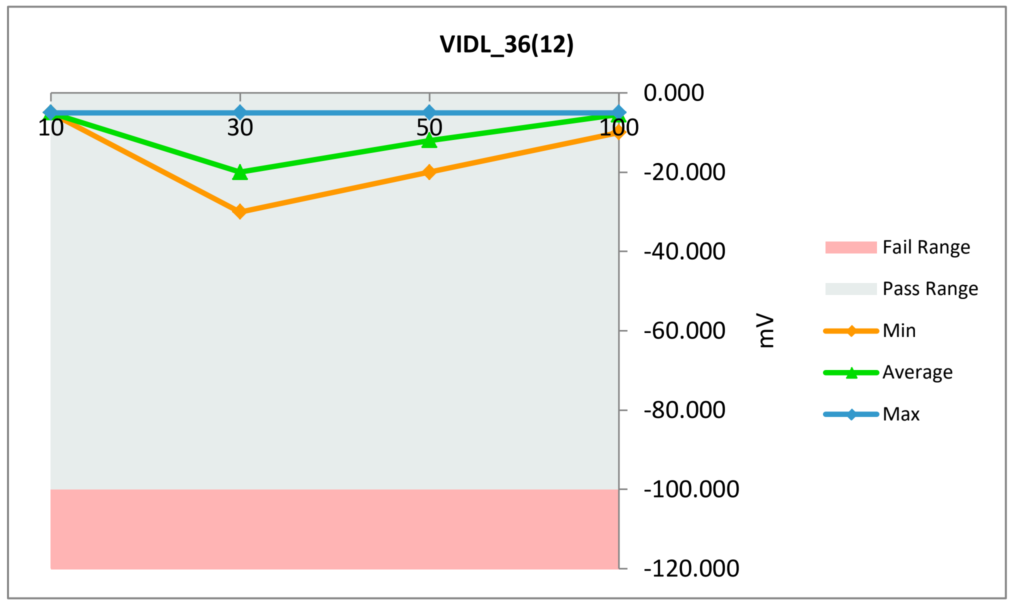
HDR Biased TID Report
SN55LVCP22A-SP

	VIDL_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	-10.000	-5.000	-5.000
10	2	-10.000	-5.000	-5.000
10	3	-10.000	-5.000	-5.000
10	4	-5.000	-5.000	0.000
10	5	-5.000	-5.000	0.000
30	1	-20.000	-15.000	-5.000
30	2	-5.000	-5.000	0.000
30	3	-30.000	-30.000	0.000
30	4	-25.000	-25.000	0.000
30	5	-30.000	-25.000	-5.000
50	11	-10.000	-20.000	10.000
50	12	-10.000	-5.000	-5.000
50	13	-20.000	-10.000	-10.000
50	14	-10.000	-5.000	-5.000
50	15	-30.000	-20.000	-10.000
100	22	-5.000	-5.000	0.000
100	23	-10.000	-5.000	-5.000
100	24	-5.000	-5.000	0.000
100	25	-20.000	-5.000	-15.000
100	26	-10.000	-5.000	-5.000
100	27	-20.000	-5.000	-15.000
100	28	-20.000	-10.000	-10.000
100	29	-10.000	-5.000	-5.000
100	30	-5.000	-5.000	0.000
100	31	-10.000	-5.000	-5.000
100	32	-5.000	-5.000	0.000
100	33	-5.000	-5.000	0.000
100	34	-10.000	-5.000	-5.000
100	35	-10.000	-5.000	-5.000
100	36	-15.000	-10.000	-5.000
100	37	-10.000	-5.000	-5.000
100	38	-10.000	-5.000	-5.000
100	39	-5.000	-5.000	0.000
100	41	-15.000	-5.000	-10.000
100	42	-5.000	-5.000	0.000
100	43	-15.000	-5.000	-10.000
100	44	-5.000	-5.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-12.297	-8.243	-4.054
	Min	-30.000	-30.000	-15.000
	Std Dev	7.601	6.792	4.836

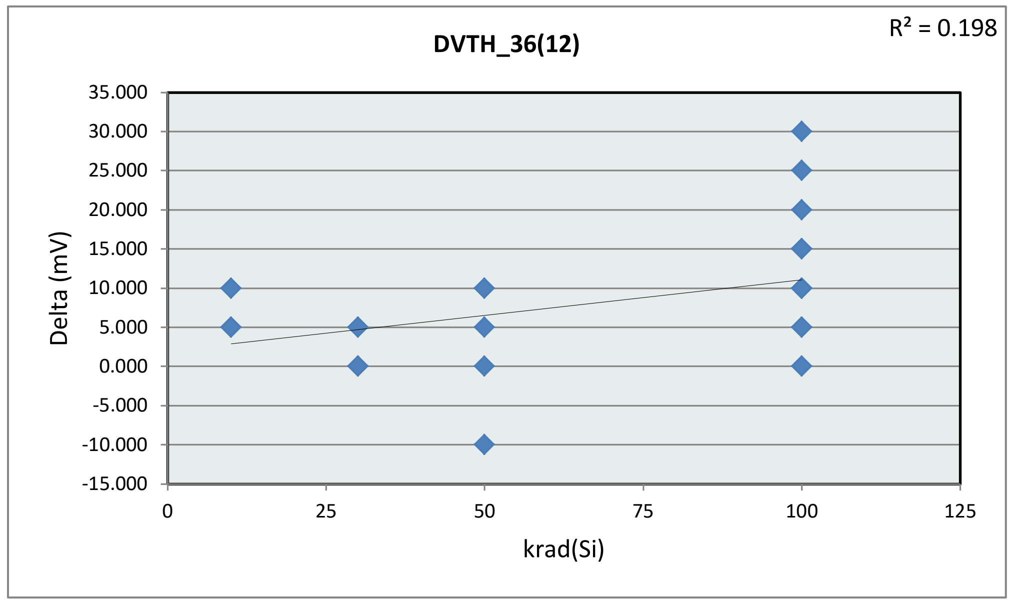


	VIDL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-30.000	-20.000	-10.000
Average	-5.000	-20.000	-12.000	-5.455
Max	-5.000	-5.000	-5.000	-5.000
UL				

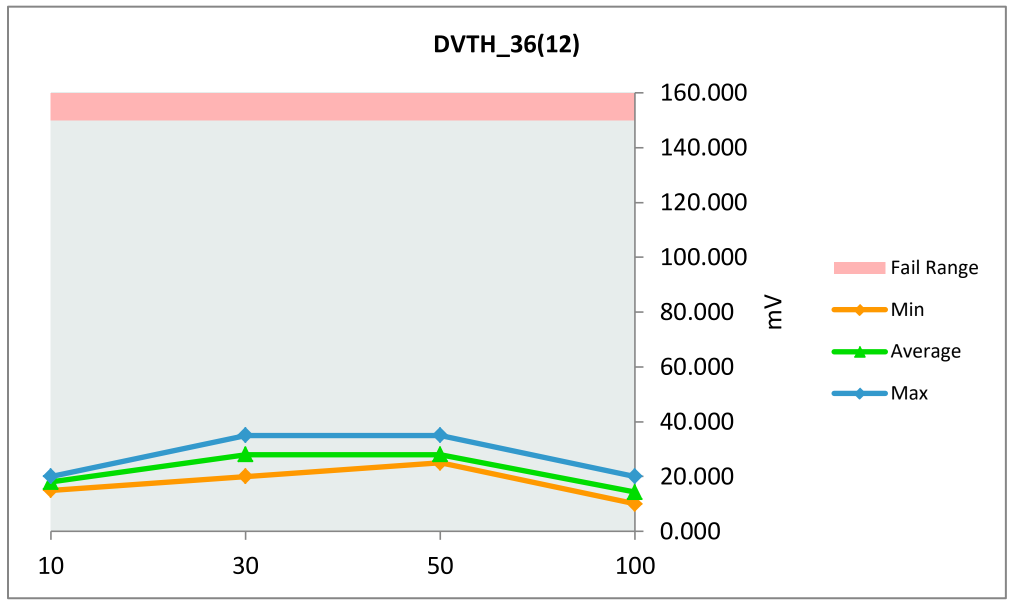


HDR Biased TID Report
SN55LVCP22A-SP

		DVTH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	30.000	20.000	10.000
10	2	25.000	20.000	5.000
10	3	25.000	15.000	10.000
10	4	25.000	20.000	5.000
10	5	20.000	15.000	5.000
30	1	25.000	20.000	5.000
30	2	25.000	25.000	0.000
30	3	35.000	35.000	0.000
30	4	30.000	30.000	0.000
30	5	35.000	30.000	5.000
50	11	35.000	25.000	10.000
50	12	35.000	30.000	5.000
50	13	25.000	35.000	-10.000
50	14	25.000	25.000	0.000
50	15	35.000	25.000	10.000
100	22	15.000	15.000	0.000
100	23	30.000	15.000	15.000
100	24	15.000	15.000	0.000
100	25	40.000	10.000	30.000
100	26	25.000	15.000	10.000
100	27	40.000	15.000	25.000
100	28	35.000	15.000	20.000
100	29	25.000	15.000	10.000
100	30	20.000	15.000	5.000
100	31	25.000	15.000	10.000
100	32	25.000	15.000	10.000
100	33	25.000	15.000	10.000
100	34	30.000	15.000	15.000
100	35	30.000	15.000	15.000
100	36	20.000	15.000	5.000
100	37	30.000	15.000	15.000
100	38	20.000	10.000	10.000
100	39	25.000	15.000	10.000
100	41	25.000	10.000	15.000
100	42	20.000	15.000	5.000
100	43	20.000	10.000	10.000
100	44	30.000	20.000	10.000
	Max	40.000	35.000	30.000
	Average	27.027	18.514	8.514
	Min	15.000	10.000	-10.000
	Std Dev	6.287	6.756	7.441

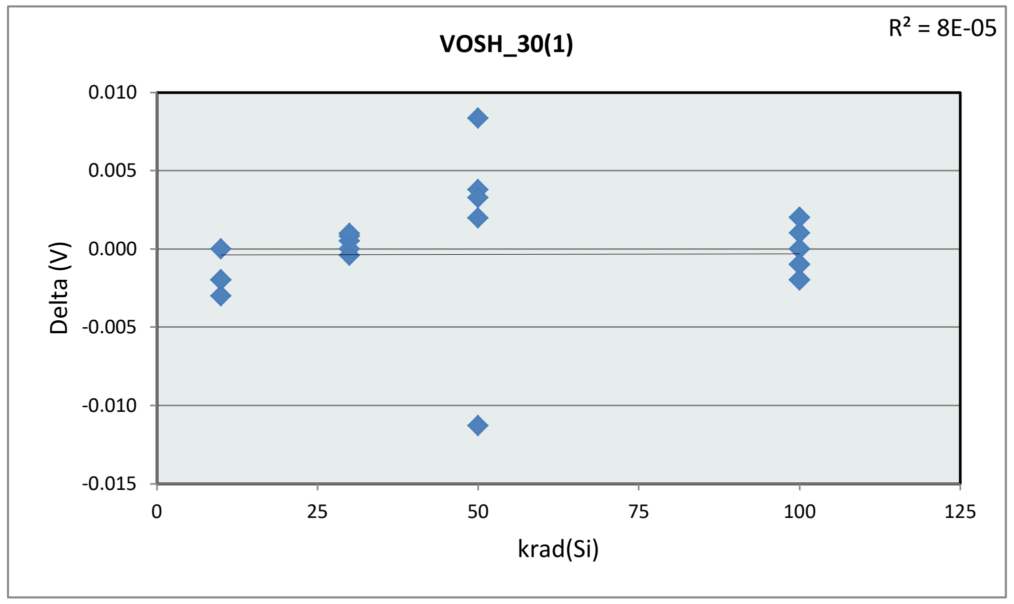


	DVTH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	20.000	25.000	10.000
Average	18.000	28.000	28.000	14.318
Max	20.000	35.000	35.000	20.000
UL	150.000	150.000	150.000	150.000

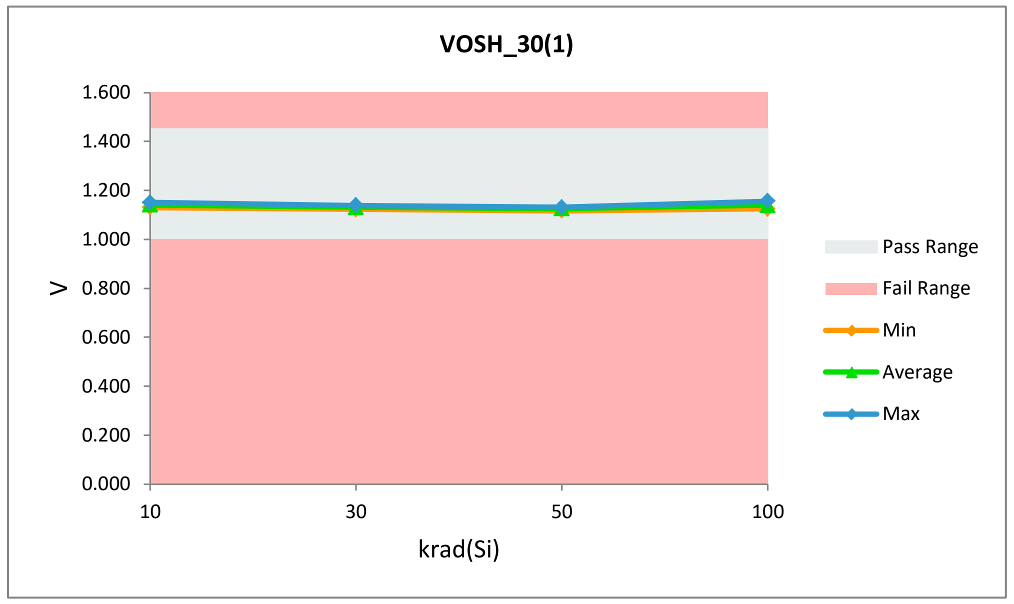


HDR Biased TID Report
SN55LVCP22A-SP

		VOSH_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.129	1.131	-0.002
10	2	1.140	1.140	0.000
10	3	1.148	1.150	-0.002
10	4	1.148	1.151	-0.003
10	5	1.128	1.130	-0.002
30	1	1.132	1.131	0.001
30	2	1.135	1.135	0.000
30	3	1.122	1.122	0.000
30	4	1.130	1.129	0.001
30	5	1.139	1.139	0.000
50	11	1.130	1.128	0.002
50	12	1.118	1.129	-0.011
50	13	1.121	1.117	0.004
50	14	1.134	1.131	0.003
50	15	1.129	1.121	0.008
100	22	1.136	1.137	-0.001
100	23	1.139	1.140	-0.001
100	24	1.148	1.150	-0.002
100	25	1.137	1.139	-0.002
100	26	1.137	1.137	0.000
100	27	1.129	1.130	-0.001
100	28	1.148	1.150	-0.002
100	29	1.128	1.129	-0.001
100	30	1.148	1.149	-0.001
100	31	1.144	1.142	0.002
100	32	1.143	1.142	0.001
100	33	1.140	1.141	-0.001
100	34	1.140	1.140	0.000
100	35	1.132	1.134	-0.002
100	36	1.139	1.139	0.000
100	37	1.145	1.147	-0.002
100	38	1.156	1.156	0.000
100	39	1.150	1.148	0.002
100	41	1.133	1.131	0.002
100	42	1.126	1.125	0.001
100	43	1.133	1.135	-0.002
100	44	1.139	1.140	-0.001
	Max	1.156	1.156	0.008
	Average	1.137	1.137	0.000
	Min	1.118	1.117	-0.011
	Std Dev	0.009	0.009	0.003

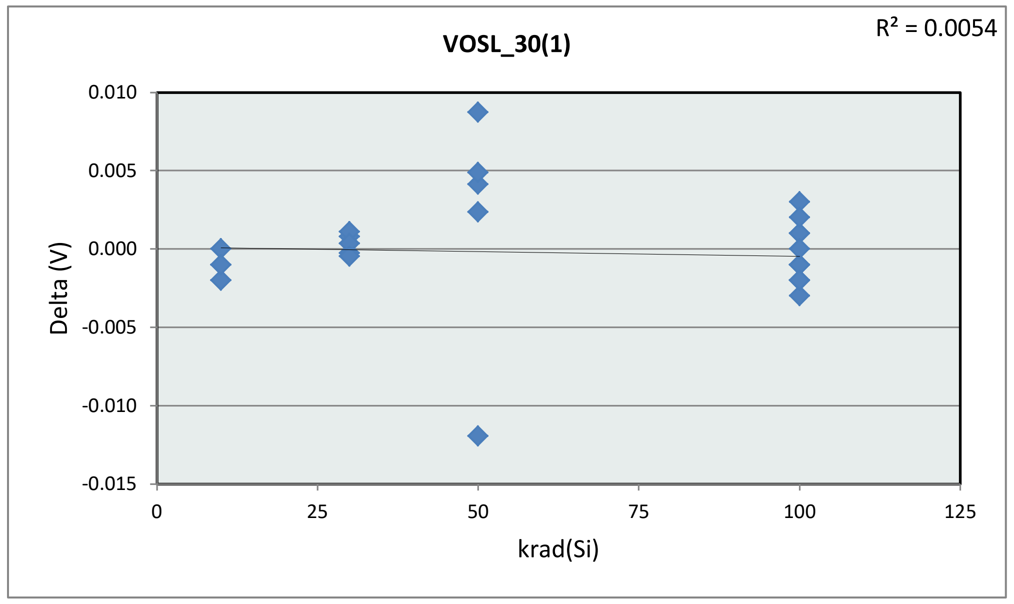


	VOSH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.130	1.122	1.117	1.125
Average	1.140	1.131	1.125	1.140
Max	1.151	1.139	1.131	1.156
UL	1.450	1.450	1.450	1.450

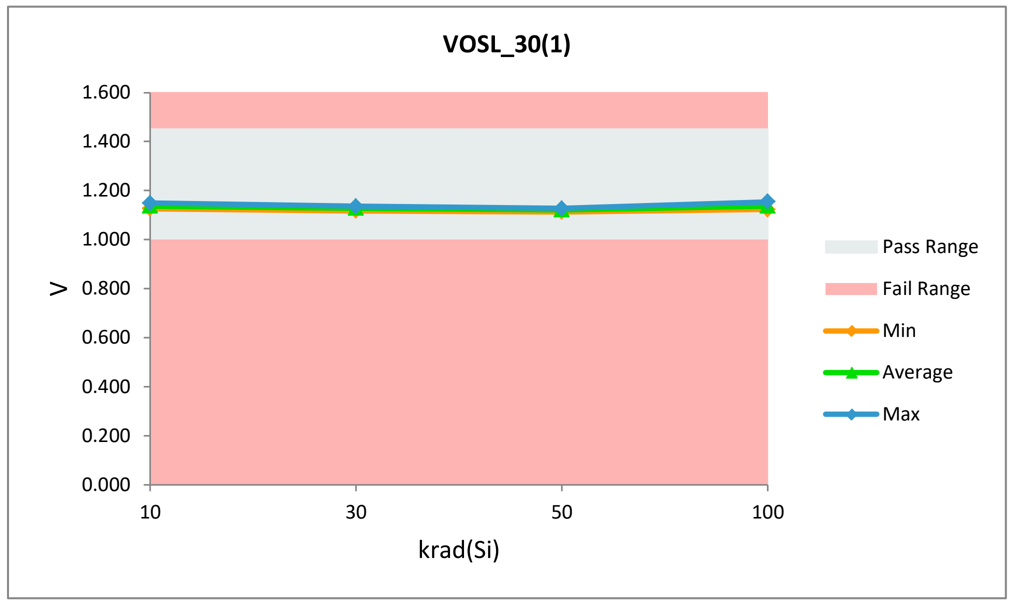


HDR Biased TID Report
SN55LVCP22A-SP

		VOSL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.126	1.128	-0.002
10	2	1.136	1.136	0.000
10	3	1.147	1.149	-0.002
10	4	1.147	1.148	-0.001
10	5	1.125	1.126	-0.001
30	1	1.129	1.128	0.001
30	2	1.133	1.132	0.001
30	3	1.118	1.118	0.000
30	4	1.126	1.126	0.000
30	5	1.136	1.136	0.000
50	11	1.126	1.124	0.002
50	12	1.114	1.126	-0.012
50	13	1.117	1.113	0.004
50	14	1.132	1.127	0.005
50	15	1.126	1.117	0.009
100	22	1.132	1.134	-0.002
100	23	1.135	1.136	-0.001
100	24	1.145	1.147	-0.002
100	25	1.134	1.136	-0.002
100	26	1.133	1.134	-0.001
100	27	1.125	1.127	-0.002
100	28	1.144	1.145	-0.001
100	29	1.124	1.127	-0.003
100	30	1.145	1.146	-0.001
100	31	1.140	1.139	0.001
100	32	1.140	1.139	0.001
100	33	1.137	1.138	-0.001
100	34	1.137	1.136	0.001
100	35	1.129	1.131	-0.002
100	36	1.136	1.135	0.001
100	37	1.143	1.144	-0.001
100	38	1.153	1.154	-0.001
100	39	1.147	1.144	0.003
100	41	1.129	1.127	0.002
100	42	1.123	1.123	0.000
100	43	1.130	1.132	-0.002
100	44	1.136	1.138	-0.002
	Max	1.153	1.154	0.009
	Average	1.133	1.134	0.000
	Min	1.114	1.113	-0.012
	Std Dev	0.009	0.009	0.003

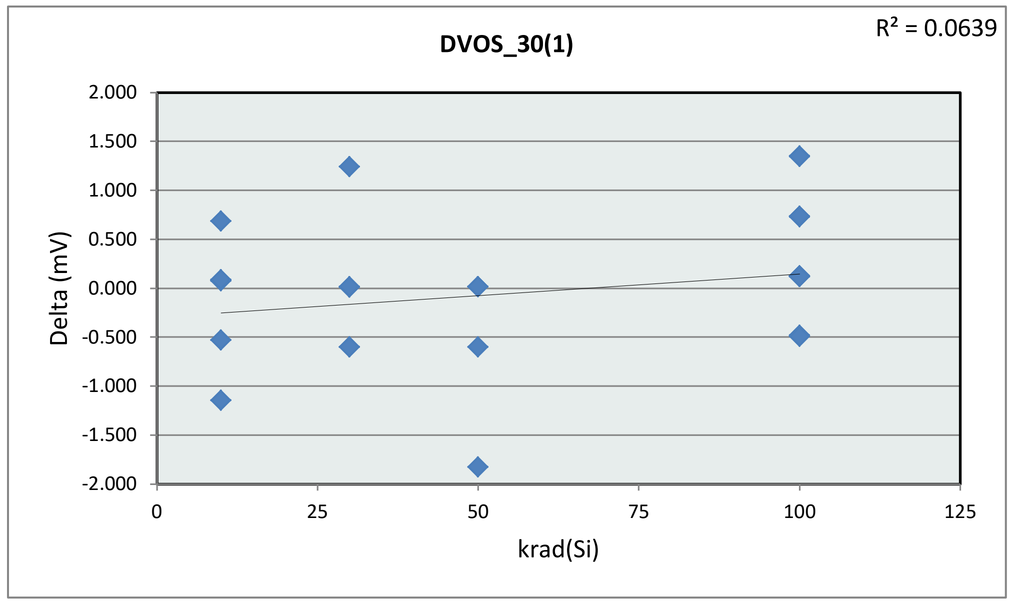


	VOSL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.126	1.118	1.113	1.123
Average	1.137	1.128	1.121	1.137
Max	1.149	1.136	1.127	1.154
UL	1.450	1.450	1.450	1.450

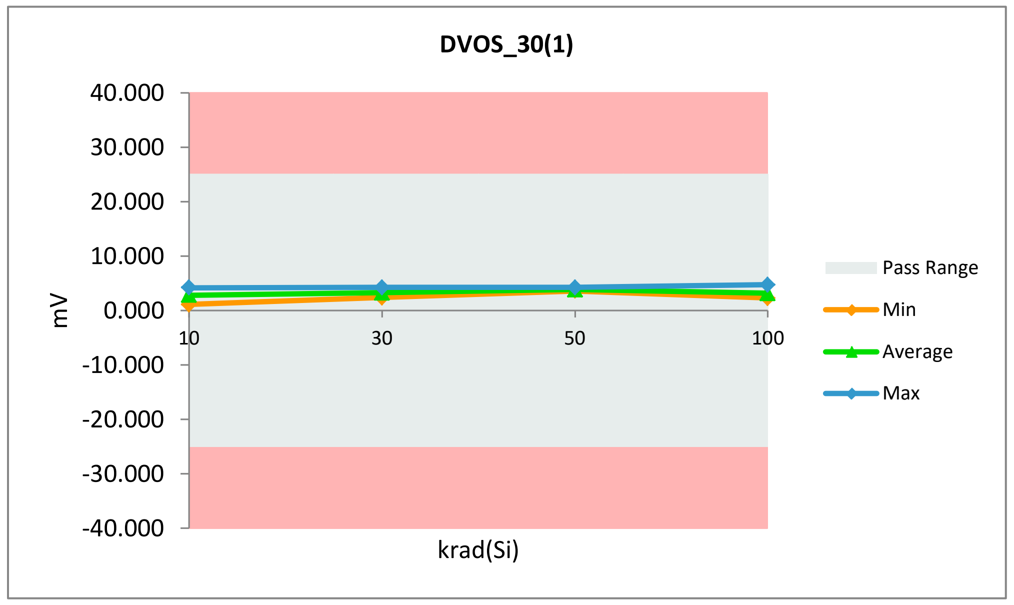


HDR Biased TID Report
SN55LVCP22A-SP

		DVOS_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	2.437	2.360	0.077
10	2	3.664	3.581	0.083
10	3	1.823	1.139	0.684
10	4	1.823	2.969	-1.146
10	5	3.663	4.191	-0.528
30	1	3.026	3.014	0.012
30	2	2.412	3.014	-0.602
30	3	4.252	4.240	0.012
30	4	3.639	2.401	1.238
30	5	3.026	3.628	-0.602
50	11	3.639	3.626	0.013
50	12	3.639	3.627	0.012
50	13	3.638	4.242	-0.604
50	14	2.411	4.241	-1.830
50	15	3.639	3.627	0.012
100	22	3.050	2.930	0.120
100	23	3.663	3.538	0.125
100	24	3.664	3.540	0.124
100	25	3.050	2.929	0.121
100	26	3.664	3.539	0.125
100	27	4.891	3.540	1.351
100	28	4.277	4.761	-0.484
100	29	3.664	2.319	1.345
100	30	3.050	2.930	0.120
100	31	3.664	2.931	0.733
100	32	3.050	2.929	0.121
100	33	3.050	2.929	0.121
100	34	3.664	4.151	-0.487
100	35	3.664	3.542	0.122
100	36	3.050	3.539	-0.489
100	37	2.436	2.930	-0.494
100	38	2.436	2.318	0.118
100	39	3.050	3.543	-0.493
100	41	4.278	4.153	0.125
100	42	3.050	2.320	0.730
100	43	3.050	2.933	0.117
100	44	3.050	2.319	0.731
	Max	4.891	4.761	1.351
	Average	3.276	3.256	0.020
	Min	1.823	1.139	-1.830
	Std Dev	0.668	0.735	0.638

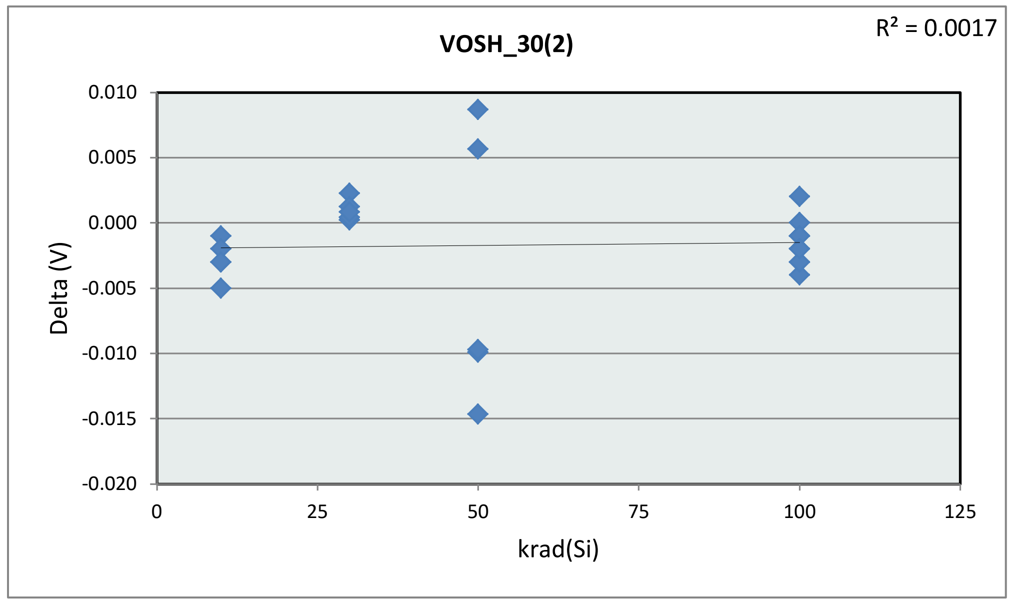


	DVOS_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	1.139	2.401	3.626	2.318
Average	2.848	3.259	3.873	3.207
Max	4.191	4.240	4.242	4.761
UL	25.000	25.000	25.000	25.000

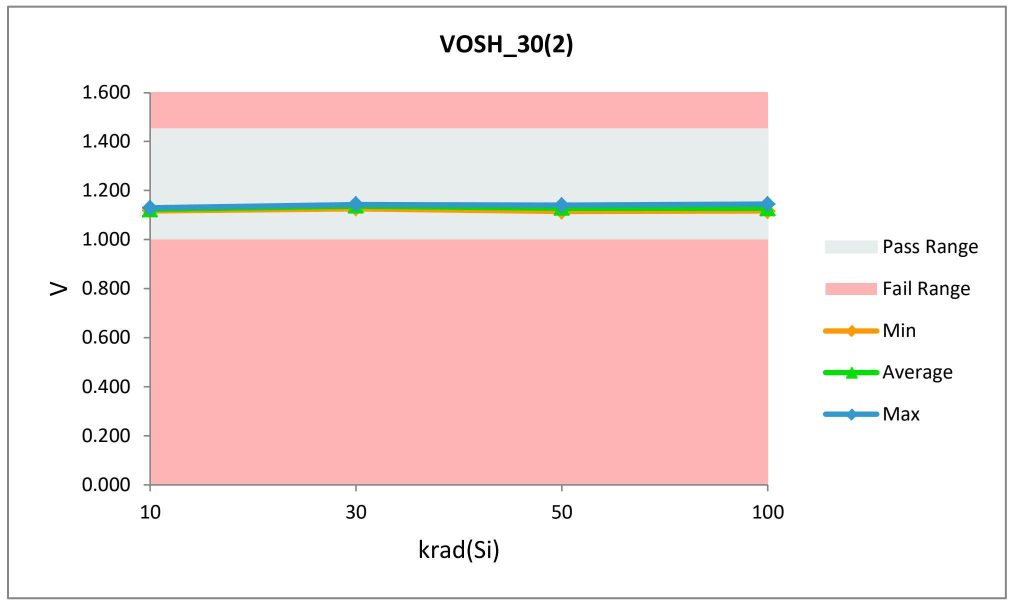


HDR Biased TID Report
SN55LVCP22A-SP

		VOSH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.118	1.119	-0.001
10	2	1.121	1.124	-0.003
10	3	1.124	1.126	-0.002
10	4	1.127	1.130	-0.003
10	5	1.113	1.118	-0.005
30	1	1.144	1.144	0.000
30	2	1.128	1.126	0.002
30	3	1.137	1.137	0.000
30	4	1.136	1.135	0.001
30	5	1.145	1.144	0.001
50	11	1.130	1.140	-0.010
50	12	1.139	1.130	0.009
50	13	1.123	1.138	-0.015
50	14	1.120	1.114	0.006
50	15	1.112	1.122	-0.010
100	22	1.125	1.126	-0.001
100	23	1.118	1.119	-0.001
100	24	1.122	1.125	-0.003
100	25	1.130	1.133	-0.003
100	26	1.122	1.123	-0.001
100	27	1.127	1.130	-0.003
100	28	1.126	1.127	-0.001
100	29	1.129	1.129	0.000
100	30	1.121	1.121	0.000
100	31	1.133	1.131	0.002
100	32	1.127	1.128	-0.001
100	33	1.119	1.123	-0.004
100	34	1.119	1.120	-0.001
100	35	1.143	1.145	-0.002
100	36	1.116	1.116	0.000
100	37	1.119	1.120	-0.001
100	38	1.121	1.122	-0.001
100	39	1.142	1.143	-0.001
100	41	1.138	1.140	-0.002
100	42	1.127	1.129	-0.002
100	43	1.124	1.127	-0.003
100	44	1.123	1.125	-0.002
	Max	1.145	1.145	0.009
	Average	1.127	1.128	-0.002
	Min	1.112	1.114	-0.015
	Std Dev	0.009	0.008	0.004

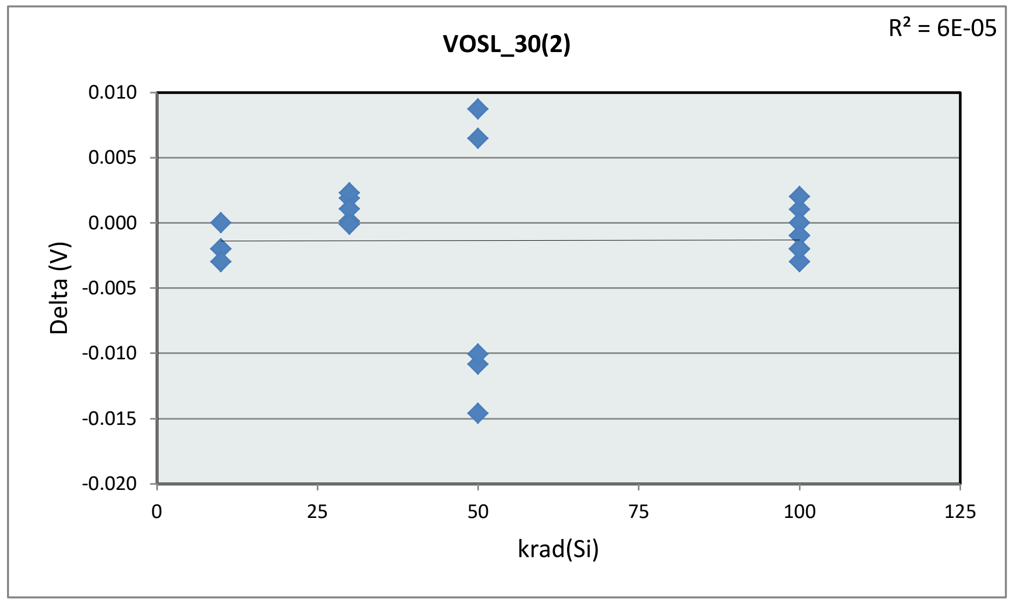


	VOSH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.118	1.126	1.114	1.116
Average	1.123	1.137	1.129	1.127
Max	1.130	1.144	1.140	1.145
UL	1.450	1.450	1.450	1.450

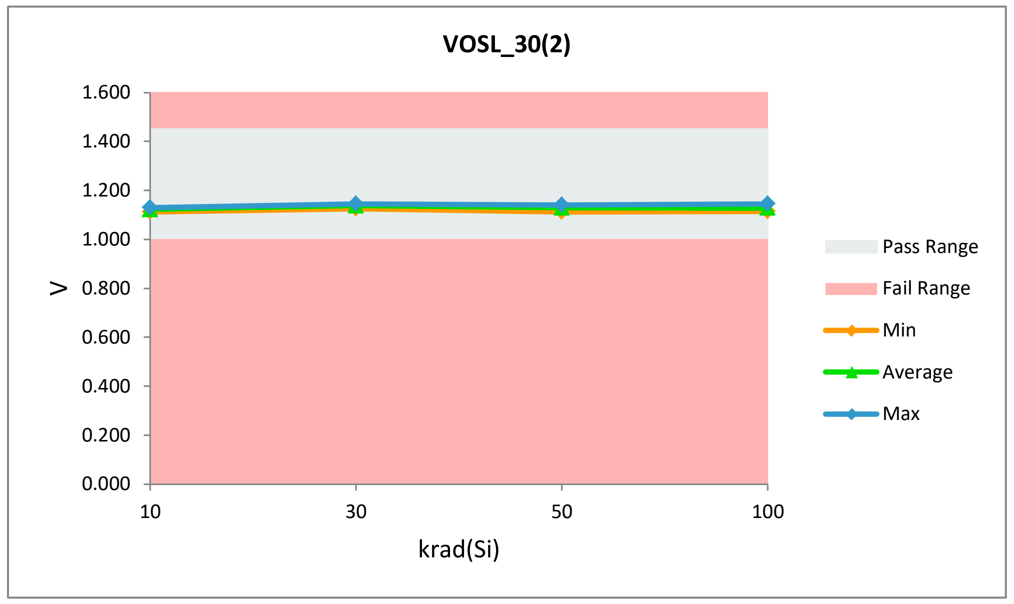


HDR Biased TID Report
SN55LVCP22A-SP

		VOSL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.117	1.119	-0.002
10	2	1.121	1.123	-0.002
10	3	1.124	1.126	-0.002
10	4	1.127	1.130	-0.003
10	5	1.113	1.113	0.000
30	1	1.145	1.143	0.002
30	2	1.128	1.126	0.002
30	3	1.138	1.138	0.000
30	4	1.135	1.134	0.001
30	5	1.145	1.145	0.000
50	11	1.130	1.141	-0.011
50	12	1.139	1.130	0.009
50	13	1.123	1.138	-0.015
50	14	1.118	1.112	0.006
50	15	1.113	1.123	-0.010
100	22	1.125	1.126	-0.001
100	23	1.118	1.119	-0.001
100	24	1.123	1.124	-0.001
100	25	1.131	1.134	-0.003
100	26	1.122	1.123	-0.001
100	27	1.128	1.129	-0.001
100	28	1.126	1.128	-0.002
100	29	1.131	1.130	0.001
100	30	1.121	1.121	0.000
100	31	1.133	1.131	0.002
100	32	1.127	1.129	-0.002
100	33	1.119	1.122	-0.003
100	34	1.120	1.120	0.000
100	35	1.143	1.145	-0.002
100	36	1.115	1.115	0.000
100	37	1.119	1.121	-0.002
100	38	1.120	1.122	-0.002
100	39	1.142	1.143	-0.001
100	41	1.138	1.140	-0.002
100	42	1.128	1.129	-0.001
100	43	1.124	1.126	-0.002
100	44	1.124	1.126	-0.002
	Max	1.145	1.145	0.009
	Average	1.127	1.128	-0.001
	Min	1.113	1.112	-0.015
	Std Dev	0.009	0.009	0.004



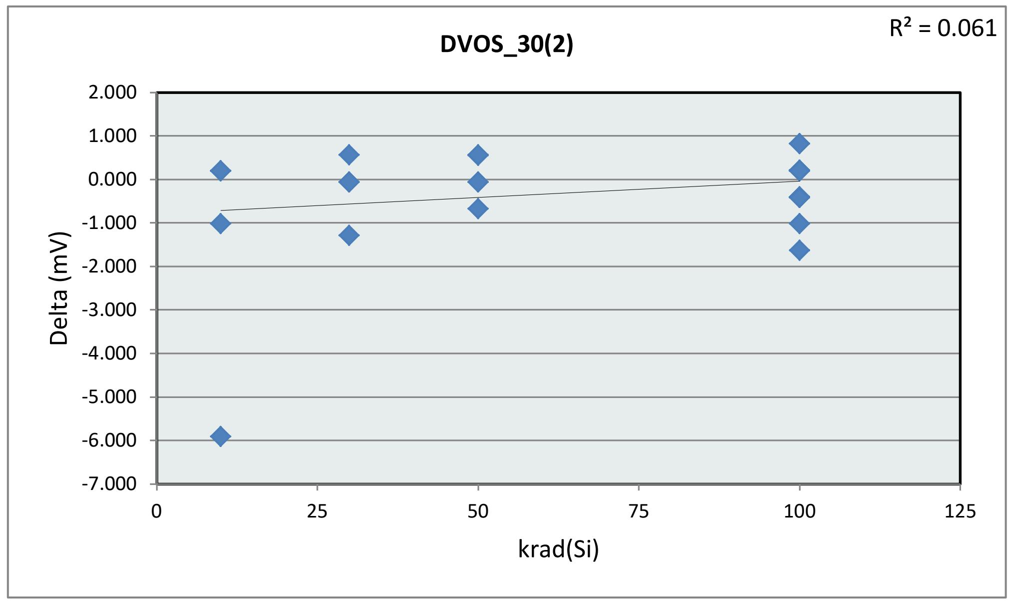
	VOSL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.113	1.126	1.112	1.115
Average	1.122	1.137	1.129	1.127
Max	1.130	1.145	1.141	1.145
UL	1.450	1.450	1.450	1.450



HDR Biased TID Report
SN55LVCP22A-SP

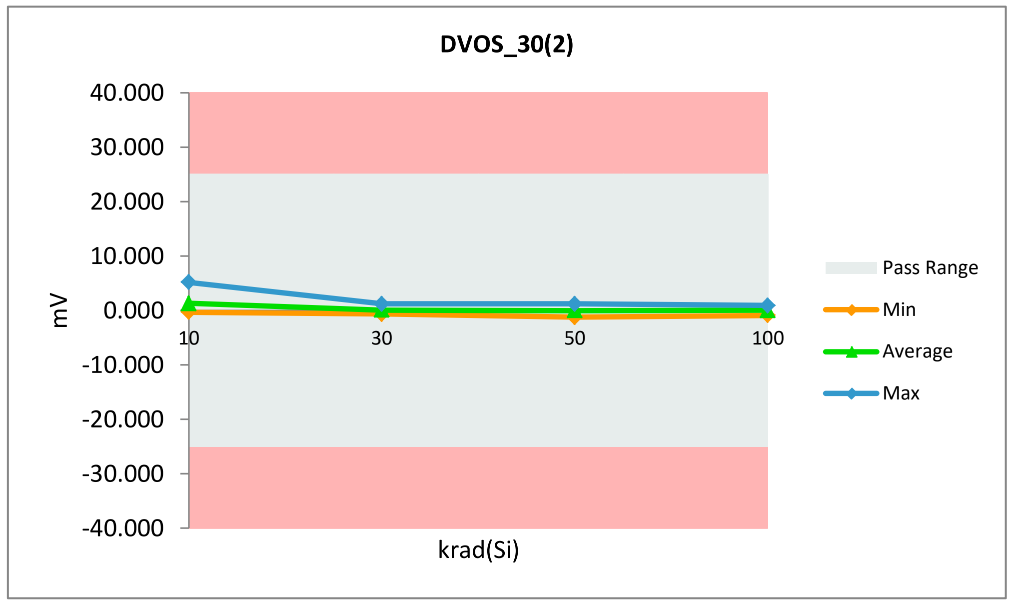
	DVOS_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	0.523	0.325	0.198
10	2	-0.092	0.935	-1.027
10	3	0.524	0.330	0.194
10	4	-0.092	-0.289	0.197
10	5	-0.706	5.212	-5.918
30	1	-0.676	0.611	-1.287
30	2	-0.063	-0.003	-0.060
30	3	-0.677	-0.616	-0.061
30	4	1.166	1.225	-0.059
30	5	-0.062	-0.616	0.554
50	11	-0.063	-0.616	0.553
50	12	-0.062	0.611	-0.673
50	13	-0.063	-0.002	-0.061
50	14	1.164	1.225	-0.061
50	15	-0.676	-1.230	0.554
100	22	-0.090	0.323	-0.414
100	23	-0.093	0.317	-0.409
100	24	-0.091	0.931	-1.022
100	25	-0.705	-0.902	0.197
100	26	0.522	0.317	0.205
100	27	-0.705	0.931	-1.636
100	28	-0.092	-0.294	0.202
100	29	-1.318	-0.900	-0.418
100	30	-0.090	0.325	-0.415
100	31	-0.091	0.321	-0.412
100	32	0.522	-0.293	0.815
100	33	0.522	0.930	-0.408
100	34	-0.705	-0.291	-0.414
100	35	-0.091	-0.290	0.199
100	36	0.522	0.318	0.203
100	37	0.523	-0.289	0.812
100	38	0.522	0.320	0.202
100	39	0.524	0.325	0.199
100	41	-0.090	-0.286	0.196
100	42	-0.705	-0.289	-0.415
100	43	0.524	0.326	0.198
100	44	-0.705	-0.901	0.196
	Max	1.166	5.212	0.815
	Average	-0.034	0.218	-0.251
	Min	-1.318	-1.230	-5.918
	Std Dev	0.568	1.048	1.102



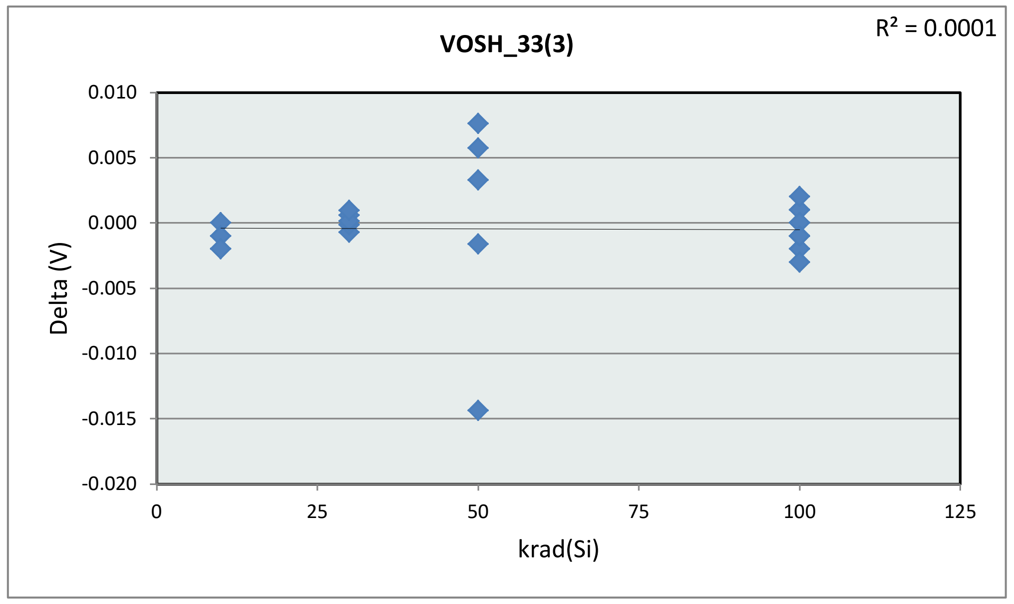
	DVOS_30(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.289	-0.616	-1.230	-0.902
Average	1.303	0.120	-0.002	0.043
Max	5.212	1.225	1.225	0.931
UL	25.000	25.000	25.000	25.000

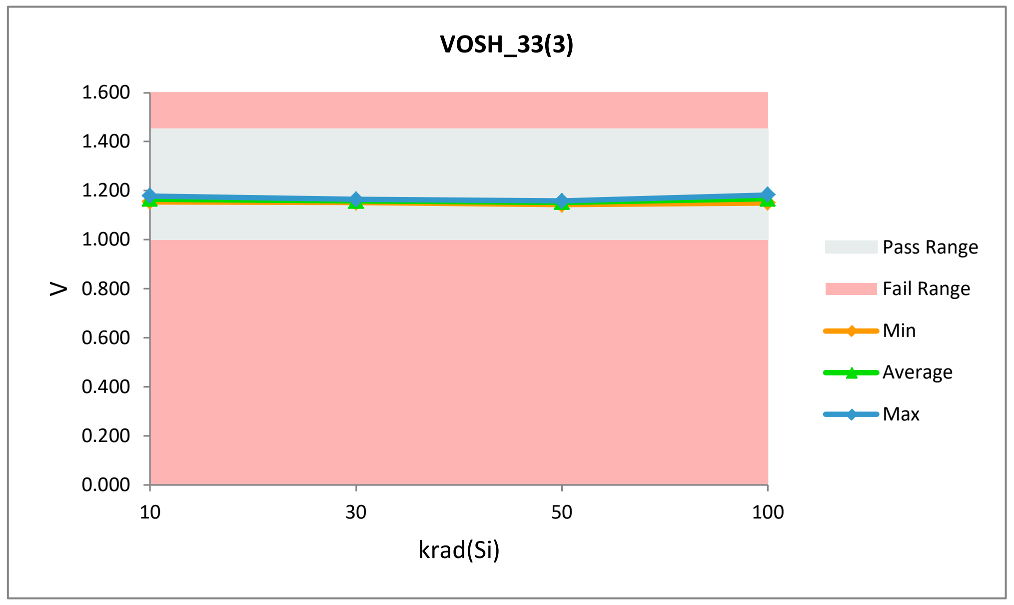


HDR Biased TID Report
SN55LVCP22A-SP

		VOSH_33(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.152	1.154	-0.002
10	2	1.166	1.166	0.000
10	3	1.173	1.174	-0.001
10	4	1.177	1.178	-0.001
10	5	1.153	1.155	-0.002
30	1	1.158	1.157	0.001
30	2	1.161	1.162	-0.001
30	3	1.151	1.151	0.000
30	4	1.155	1.155	0.000
30	5	1.165	1.164	0.001
50	11	1.156	1.158	-0.002
50	12	1.142	1.156	-0.014
50	13	1.150	1.142	0.008
50	14	1.161	1.158	0.003
50	15	1.156	1.150	0.006
100	22	1.161	1.161	0.000
100	23	1.167	1.169	-0.002
100	24	1.176	1.178	-0.002
100	25	1.165	1.165	0.000
100	26	1.163	1.164	-0.001
100	27	1.157	1.158	-0.001
100	28	1.177	1.178	-0.001
100	29	1.151	1.152	-0.001
100	30	1.174	1.175	-0.001
100	31	1.168	1.167	0.001
100	32	1.169	1.168	0.001
100	33	1.168	1.169	-0.001
100	34	1.167	1.166	0.001
100	35	1.158	1.159	-0.001
100	36	1.169	1.169	0.000
100	37	1.172	1.175	-0.003
100	38	1.183	1.183	0.000
100	39	1.173	1.171	0.002
100	41	1.156	1.156	0.000
100	42	1.150	1.150	0.000
100	43	1.155	1.158	-0.003
100	44	1.165	1.166	-0.001
	Max	1.183	1.183	0.008
	Average	1.163	1.163	0.000
	Min	1.142	1.142	-0.014
	Std Dev	0.009	0.009	0.003

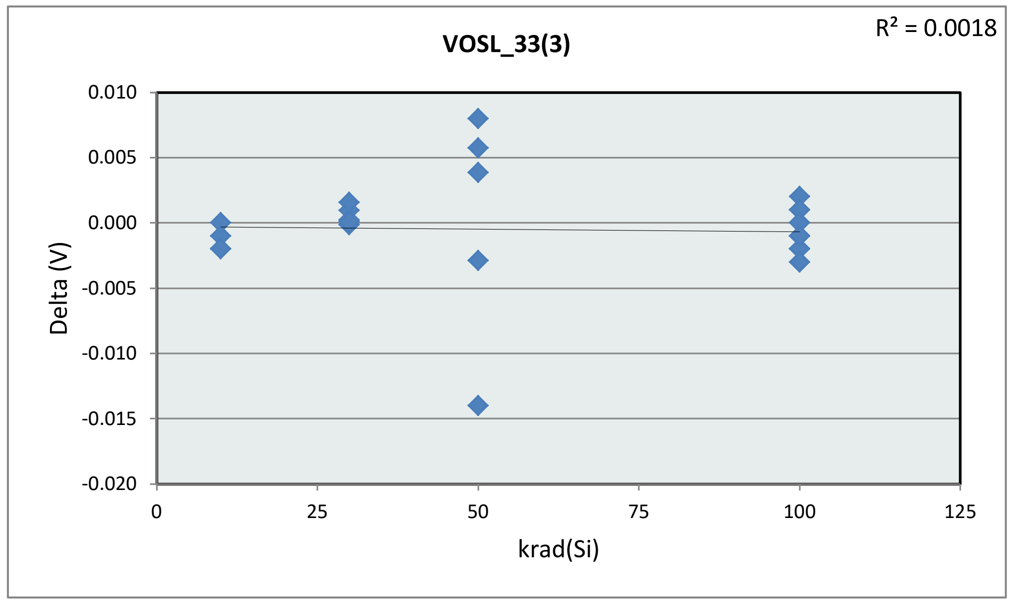


	VOSH_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.154	1.151	1.142	1.150
Average	1.165	1.158	1.153	1.166
Max	1.178	1.164	1.158	1.183
UL	1.450	1.450	1.450	1.450

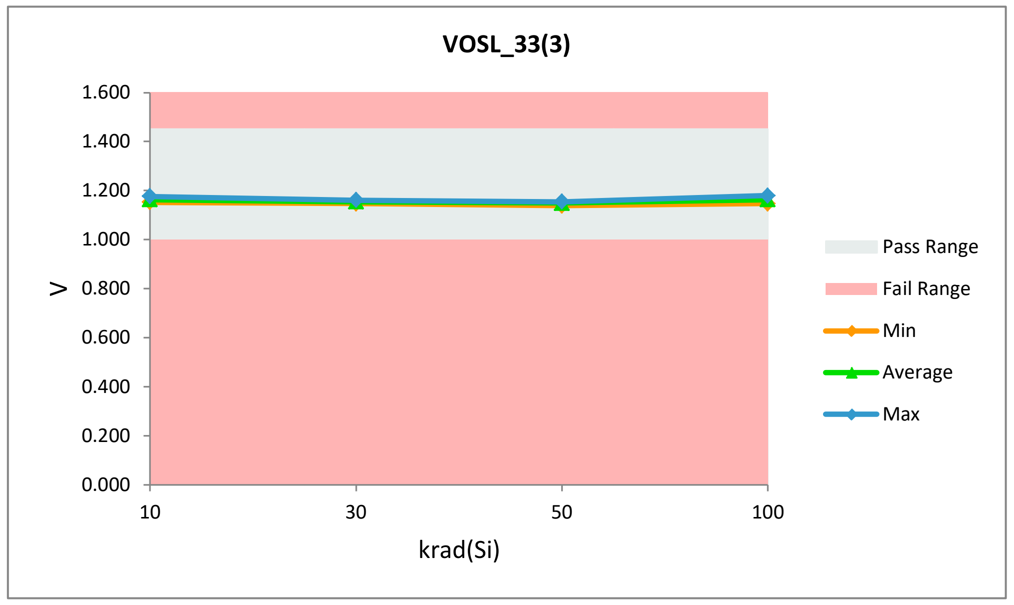


HDR Biased TID Report
SN55LVCP22A-SP

		VOSL_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.150	1.152	-0.002
10	2	1.163	1.163	0.000
10	3	1.171	1.172	-0.001
10	4	1.174	1.176	-0.002
10	5	1.150	1.152	-0.002
30	1	1.154	1.153	0.001
30	2	1.159	1.159	0.000
30	3	1.147	1.147	0.000
30	4	1.152	1.152	0.000
30	5	1.163	1.161	0.002
50	11	1.152	1.155	-0.003
50	12	1.138	1.152	-0.014
50	13	1.146	1.138	0.008
50	14	1.159	1.155	0.004
50	15	1.153	1.147	0.006
100	22	1.158	1.159	-0.001
100	23	1.164	1.165	-0.001
100	24	1.173	1.175	-0.002
100	25	1.161	1.162	-0.001
100	26	1.159	1.161	-0.002
100	27	1.153	1.155	-0.002
100	28	1.173	1.174	-0.001
100	29	1.147	1.149	-0.002
100	30	1.171	1.172	-0.001
100	31	1.165	1.164	0.001
100	32	1.166	1.166	0.000
100	33	1.164	1.166	-0.002
100	34	1.164	1.162	0.002
100	35	1.155	1.156	-0.001
100	36	1.165	1.165	0.000
100	37	1.169	1.172	-0.003
100	38	1.181	1.180	0.001
100	39	1.169	1.168	0.001
100	41	1.153	1.152	0.001
100	42	1.147	1.147	0.000
100	43	1.152	1.155	-0.003
100	44	1.162	1.163	-0.001
	Max	1.181	1.180	0.008
	Average	1.159	1.160	-0.001
	Min	1.138	1.138	-0.014
	Std Dev	0.010	0.010	0.003

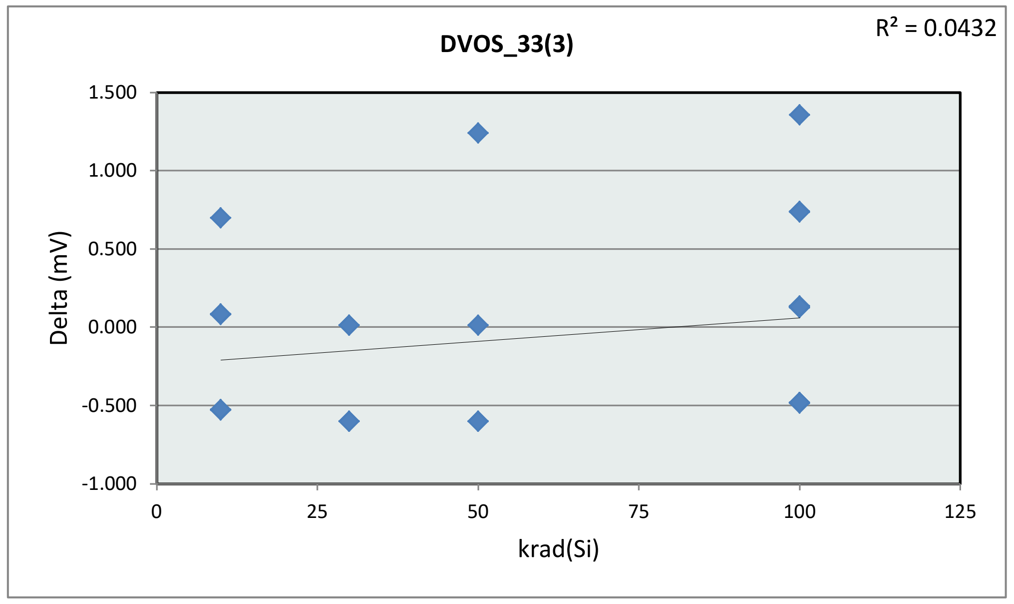


	VOSL_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.152	1.147	1.138	1.147
Average	1.163	1.154	1.149	1.163
Max	1.176	1.161	1.155	1.180
UL	1.450	1.450	1.450	1.450

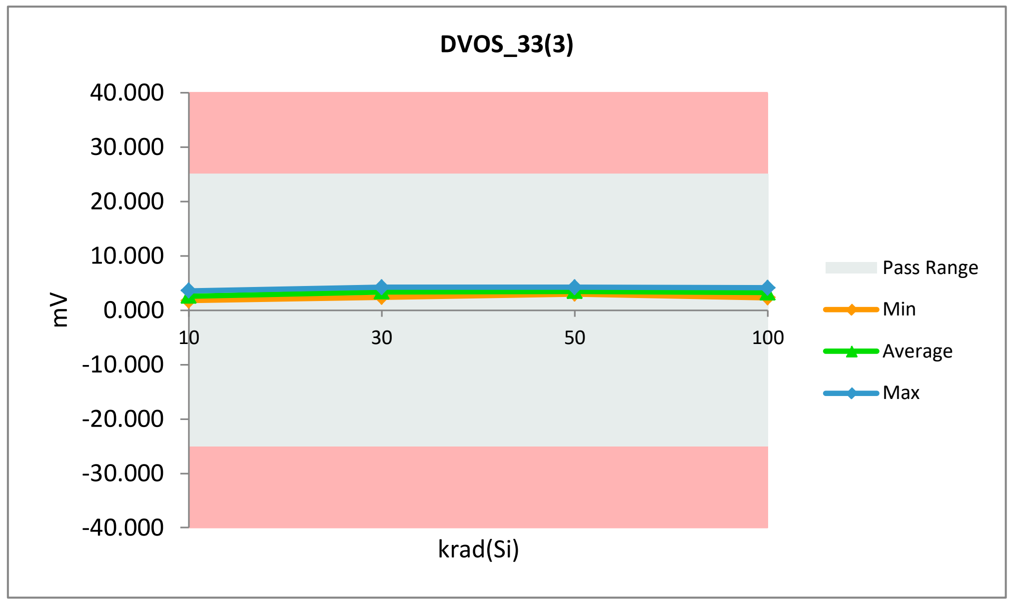


HDR Biased TID Report
SN55LVCP22A-SP

		DVOS_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.822	2.353	-0.531
10	2	3.049	3.575	-0.526
10	3	1.822	1.743	0.079
10	4	2.435	2.353	0.082
10	5	3.662	2.964	0.698
30	1	3.636	4.237	-0.601
30	2	2.409	2.397	0.012
30	3	3.636	4.237	-0.601
30	4	3.022	3.010	0.012
30	5	2.409	3.010	-0.601
50	11	4.250	3.010	1.240
50	12	3.636	3.624	0.012
50	13	3.636	4.238	-0.602
50	14	2.409	3.010	-0.601
50	15	3.023	3.624	-0.601
100	22	3.049	2.311	0.738
100	23	3.049	3.532	-0.483
100	24	3.049	3.531	-0.482
100	25	4.276	2.921	1.355
100	26	3.662	3.532	0.130
100	27	3.662	3.532	0.130
100	28	4.276	4.143	0.133
100	29	3.663	3.533	0.130
100	30	3.049	2.921	0.128
100	31	3.049	3.532	-0.483
100	32	3.049	2.310	0.739
100	33	3.663	3.533	0.130
100	34	3.049	3.532	-0.483
100	35	3.049	2.922	0.127
100	36	3.662	4.143	-0.481
100	37	3.049	2.921	0.128
100	38	2.435	2.921	-0.486
100	39	3.662	3.533	0.129
100	41	3.663	4.145	-0.482
100	42	3.049	2.313	0.736
100	43	3.049	2.923	0.126
100	44	3.049	2.921	0.128
	Max	4.276	4.238	1.355
	Average	3.191	3.216	-0.025
	Min	1.822	1.743	-0.602
	Std Dev	0.603	0.639	0.528



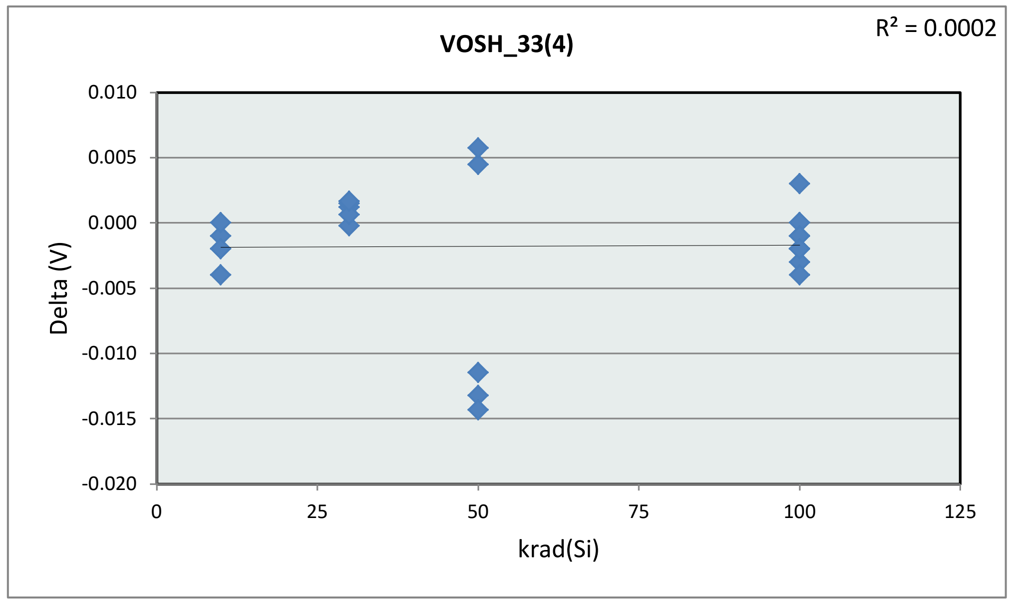
	DVOS_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	1.743	2.397	3.010	2.310
Average	2.598	3.378	3.501	3.255
Max	3.575	4.237	4.238	4.145
UL	25.000	25.000	25.000	25.000



HDR Biased TID Report
SN55LVCP22A-SP

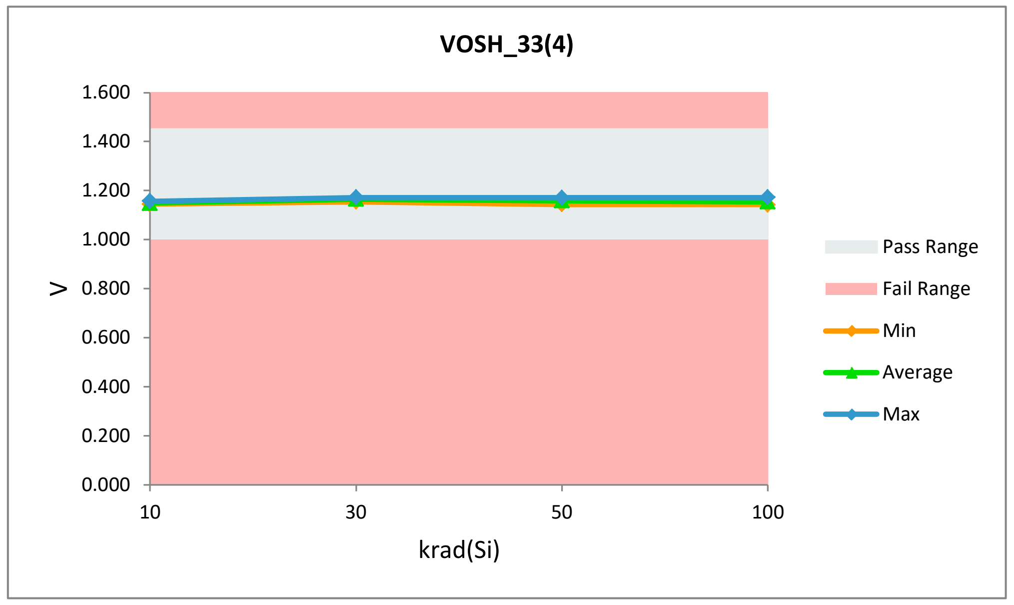
	VOSH_33(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.143	1.145	-0.002
10	2	1.148	1.149	-0.001
10	3	1.149	1.149	0.000
10	4	1.155	1.157	-0.002
10	5	1.141	1.145	-0.004
30	1	1.171	1.170	0.001
30	2	1.156	1.155	0.001
30	3	1.169	1.169	0.000
30	4	1.163	1.162	0.001
30	5	1.174	1.172	0.002
50	11	1.160	1.171	-0.011
50	12	1.164	1.160	0.004
50	13	1.153	1.166	-0.013
50	14	1.150	1.144	0.006
50	15	1.139	1.153	-0.014
100	22	1.150	1.150	0.000
100	23	1.150	1.152	-0.002
100	24	1.151	1.153	-0.002
100	25	1.157	1.159	-0.002
100	26	1.150	1.152	-0.002
100	27	1.155	1.158	-0.003
100	28	1.154	1.155	-0.001
100	29	1.154	1.154	0.000
100	30	1.145	1.146	-0.001
100	31	1.160	1.157	0.003
100	32	1.154	1.157	-0.003
100	33	1.148	1.152	-0.004
100	34	1.145	1.146	-0.001
100	35	1.170	1.172	-0.002
100	36	1.142	1.142	0.000
100	37	1.145	1.147	-0.002
100	38	1.148	1.149	-0.001
100	39	1.166	1.168	-0.002
100	41	1.163	1.165	-0.002
100	42	1.153	1.155	-0.002
100	43	1.149	1.150	-0.001
100	44	1.149	1.151	-0.002
	Max	1.174	1.172	0.006
	Average	1.154	1.156	-0.002
	Min	1.139	1.142	-0.014
	Std Dev	0.009	0.009	0.004



	VOSH_33(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	1.45	V
Min Limit	1	V

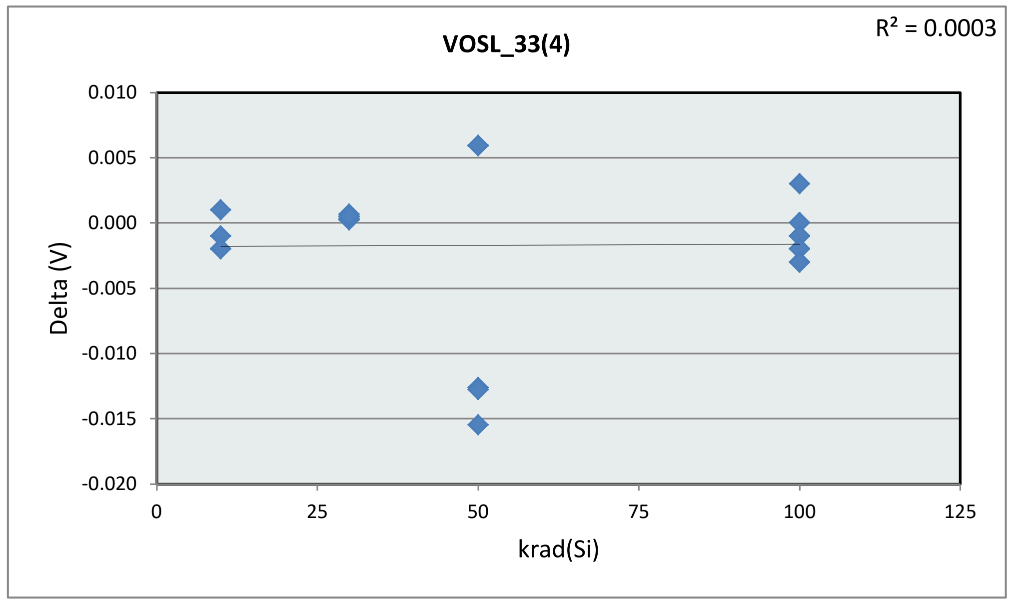
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.145	1.155	1.144	1.142
Average	1.149	1.166	1.159	1.154
Max	1.157	1.172	1.171	1.172
UL	1.450	1.450	1.450	1.450



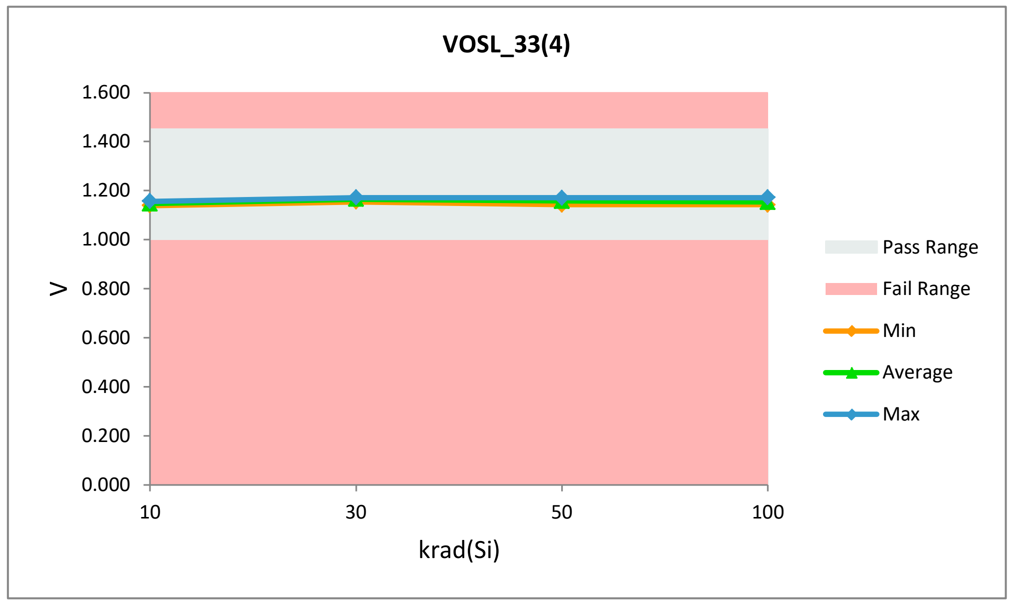
HDR Biased TID Report
SN55LVCP22A-SP

	VOSL_33(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.142	1.144	-0.002
10	2	1.147	1.149	-0.002
10	3	1.147	1.148	-0.001
10	4	1.155	1.157	-0.002
10	5	1.140	1.139	0.001
30	1	1.171	1.170	0.001
30	2	1.155	1.155	0.000
30	3	1.168	1.168	0.000
30	4	1.161	1.161	0.000
30	5	1.173	1.172	0.000
50	11	1.158	1.171	-0.013
50	12	1.164	1.158	0.006
50	13	1.152	1.165	-0.013
50	14	1.148	1.142	0.006
50	15	1.138	1.153	-0.015
100	22	1.150	1.150	0.000
100	23	1.150	1.151	-0.001
100	24	1.150	1.152	-0.002
100	25	1.157	1.159	-0.002
100	26	1.149	1.150	-0.001
100	27	1.154	1.157	-0.003
100	28	1.153	1.154	-0.001
100	29	1.154	1.154	0.000
100	30	1.143	1.144	-0.001
100	31	1.159	1.156	0.003
100	32	1.153	1.156	-0.003
100	33	1.148	1.151	-0.003
100	34	1.145	1.145	0.000
100	35	1.170	1.172	-0.002
100	36	1.142	1.142	0.000
100	37	1.144	1.146	-0.002
100	38	1.147	1.148	-0.001
100	39	1.164	1.165	-0.001
100	41	1.162	1.165	-0.003
100	42	1.153	1.154	-0.001
100	43	1.148	1.150	-0.002
100	44	1.148	1.151	-0.003
	Max	1.173	1.172	0.006
	Average	1.153	1.155	-0.002
	Min	1.138	1.139	-0.015
	Std Dev	0.009	0.009	0.004

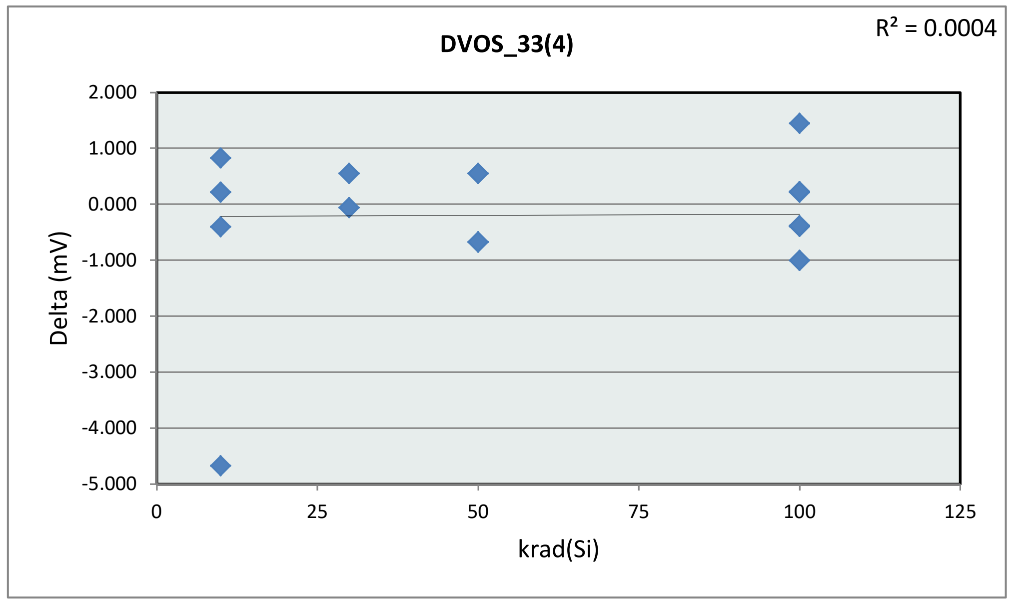


	VOSL_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.139	1.155	1.142	1.142
Average	1.147	1.165	1.158	1.153
Max	1.157	1.172	1.171	1.172
UL	1.450	1.450	1.450	1.450

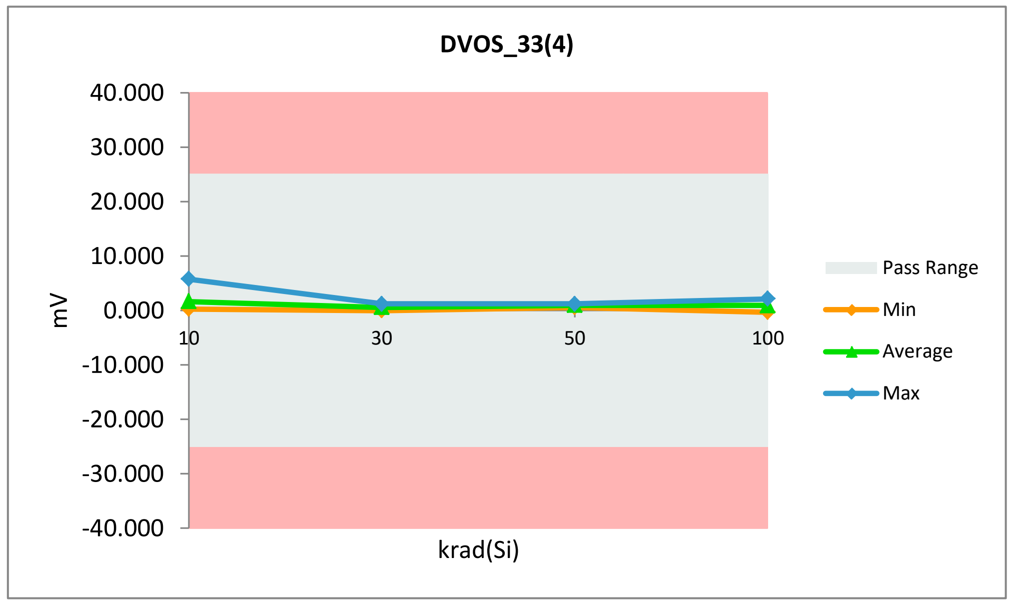


HDR Biased TID Report
SN55LVCP22A-SP

		DVOS_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.130	0.915	0.215
10	2	0.515	0.302	0.213
10	3	1.743	0.915	0.828
10	4	-0.098	0.305	-0.403
10	5	1.129	5.803	-4.674
30	1	0.546	-0.003	0.549
30	2	1.161	0.611	0.550
30	3	0.546	0.611	-0.065
30	4	1.160	1.225	-0.065
30	5	1.160	0.611	0.549
50	11	1.161	0.611	0.550
50	12	0.546	1.225	-0.679
50	13	0.547	1.225	-0.678
50	14	1.775	1.225	0.550
50	15	1.161	0.611	0.550
100	22	0.516	0.912	-0.396
100	23	0.517	0.914	-0.397
100	24	1.129	1.522	-0.393
100	25	0.515	0.298	0.217
100	26	1.129	1.522	-0.393
100	27	0.515	1.520	-1.005
100	28	0.515	0.909	-0.394
100	29	-0.098	0.301	-0.399
100	30	1.130	1.522	-0.392
100	31	0.515	0.909	-0.394
100	32	1.129	0.909	0.220
100	33	0.517	0.917	-0.399
100	34	0.515	0.909	-0.394
100	35	-0.099	0.296	-0.395
100	36	-0.098	0.911	-1.009
100	37	0.516	1.524	-1.008
100	38	1.131	0.916	0.215
100	39	1.743	2.132	-0.389
100	41	0.516	0.301	0.216
100	42	0.516	0.301	0.215
100	43	1.130	0.912	0.218
100	44	1.129	-0.312	1.441
	Max	1.775	5.803	1.441
	Average	0.790	0.979	-0.190
	Min	-0.099	-0.312	-4.674
	Std Dev	0.495	0.956	0.935

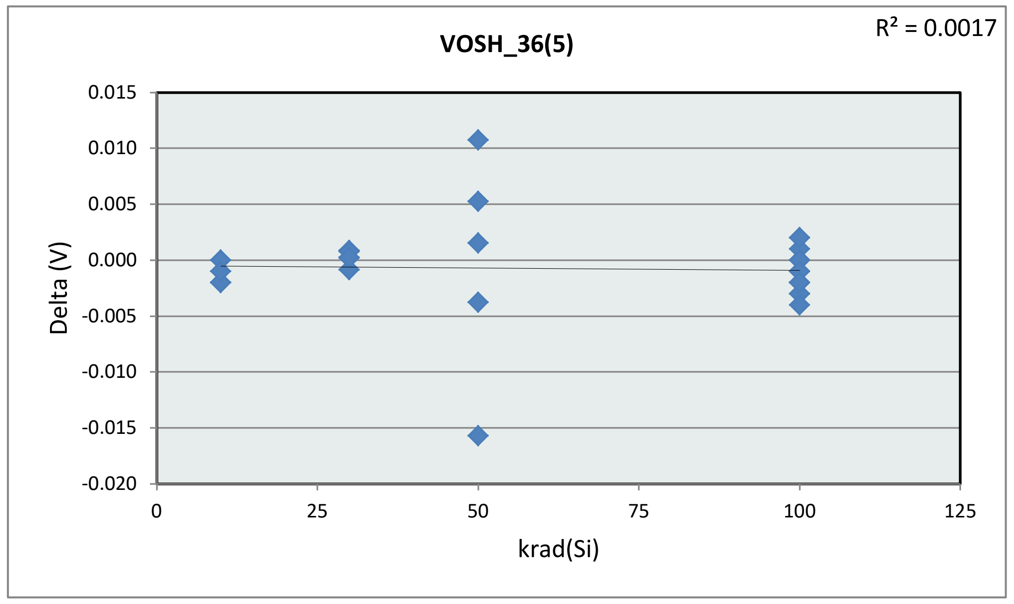


	DVOS_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.302	-0.003	0.611	-0.312
Average	1.648	0.611	0.979	0.911
Max	5.803	1.225	1.225	2.132
UL	25.000	25.000	25.000	25.000

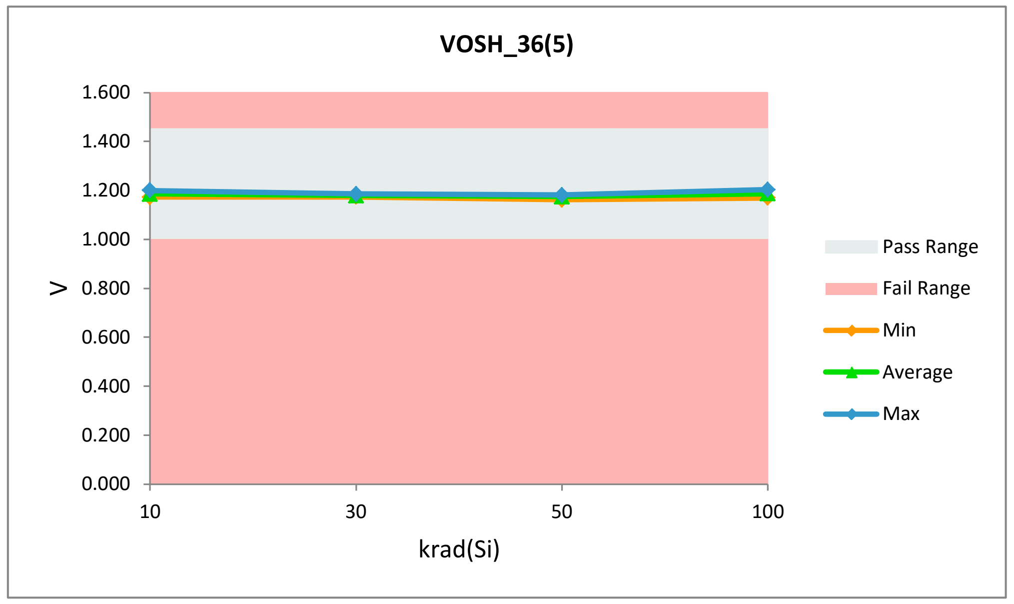


HDR Biased TID Report
SN55LVCP22A-SP

		VOSH_36(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.170	1.172	-0.002
10	2	1.186	1.186	0.000
10	3	1.190	1.192	-0.002
10	4	1.198	1.200	-0.002
10	5	1.174	1.175	-0.001
30	1	1.178	1.177	0.001
30	2	1.182	1.183	-0.001
30	3	1.174	1.174	0.000
30	4	1.175	1.174	0.001
30	5	1.185	1.185	0.000
50	11	1.177	1.181	-0.004
50	12	1.161	1.177	-0.016
50	13	1.172	1.161	0.011
50	14	1.182	1.180	0.002
50	15	1.177	1.172	0.005
100	22	1.181	1.181	0.000
100	23	1.188	1.191	-0.003
100	24	1.198	1.199	-0.001
100	25	1.184	1.186	-0.002
100	26	1.183	1.185	-0.002
100	27	1.178	1.180	-0.002
100	28	1.198	1.200	-0.002
100	29	1.167	1.170	-0.003
100	30	1.194	1.195	-0.001
100	31	1.186	1.186	0.000
100	32	1.190	1.189	0.001
100	33	1.188	1.189	-0.001
100	34	1.186	1.186	0.000
100	35	1.176	1.178	-0.002
100	36	1.191	1.192	-0.001
100	37	1.192	1.196	-0.004
100	38	1.203	1.203	0.000
100	39	1.191	1.189	0.002
100	41	1.176	1.174	0.002
100	42	1.169	1.169	0.000
100	43	1.174	1.175	-0.001
100	44	1.184	1.186	-0.002
	Max	1.203	1.203	0.011
	Average	1.183	1.183	-0.001
	Min	1.161	1.161	-0.016
	Std Dev	0.010	0.010	0.004

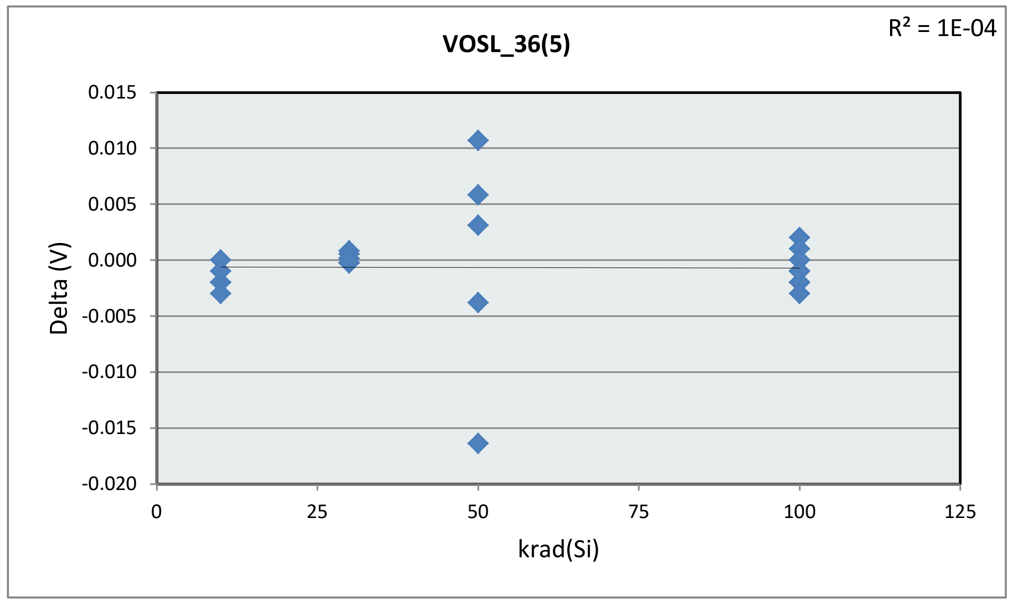


	VOSH_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.172	1.174	1.161	1.169
Average	1.185	1.179	1.174	1.186
Max	1.200	1.185	1.181	1.203
UL	1.450	1.450	1.450	1.450

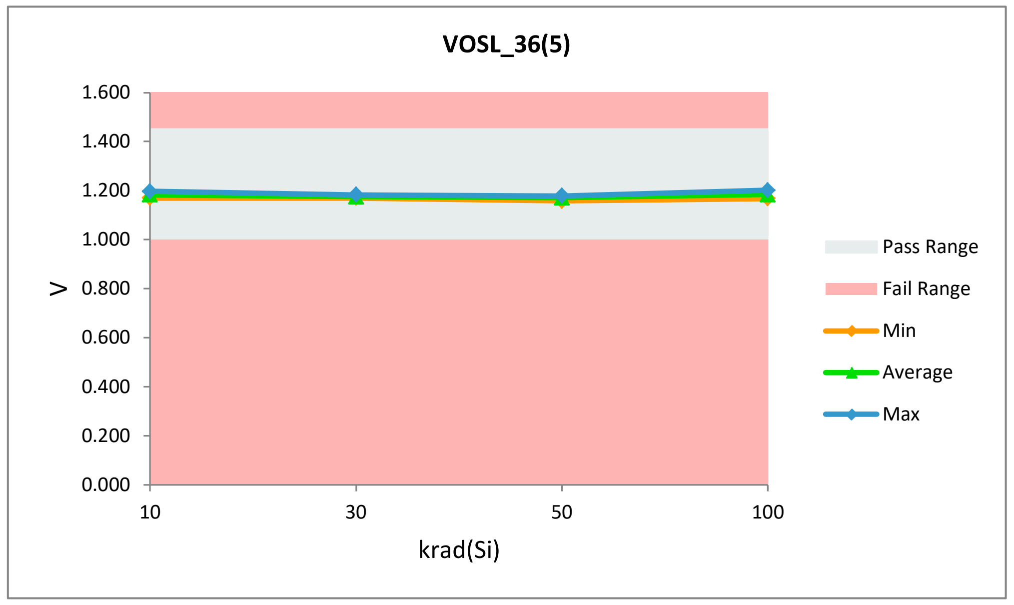


HDR Biased TID Report
SN55LVCP22A-SP

		VOSL_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W anı	Delta
10	1	1.168	1.170	-0.002
10	2	1.183	1.183	0.000
10	3	1.189	1.191	-0.002
10	4	1.194	1.197	-0.003
10	5	1.171	1.172	-0.001
30	1	1.175	1.174	0.001
30	2	1.180	1.180	0.000
30	3	1.171	1.170	0.001
30	4	1.171	1.171	0.000
30	5	1.183	1.183	0.000
50	11	1.174	1.178	-0.004
50	12	1.158	1.174	-0.016
50	13	1.169	1.158	0.011
50	14	1.179	1.176	0.003
50	15	1.175	1.169	0.006
100	22	1.179	1.179	0.000
100	23	1.186	1.187	-0.001
100	24	1.194	1.196	-0.002
100	25	1.181	1.183	-0.002
100	26	1.180	1.182	-0.002
100	27	1.175	1.177	-0.002
100	28	1.194	1.196	-0.002
100	29	1.166	1.167	-0.001
100	30	1.191	1.192	-0.001
100	31	1.183	1.183	0.000
100	32	1.186	1.186	0.000
100	33	1.185	1.186	-0.001
100	34	1.183	1.183	0.000
100	35	1.174	1.175	-0.001
100	36	1.188	1.189	-0.001
100	37	1.190	1.193	-0.003
100	38	1.201	1.201	0.000
100	39	1.188	1.186	0.002
100	41	1.172	1.171	0.001
100	42	1.167	1.167	0.000
100	43	1.171	1.172	-0.001
100	44	1.182	1.183	-0.001
	Max	1.201	1.201	0.011
	Average	1.180	1.181	-0.001
	Min	1.158	1.158	-0.016
	Std Dev	0.010	0.010	0.004

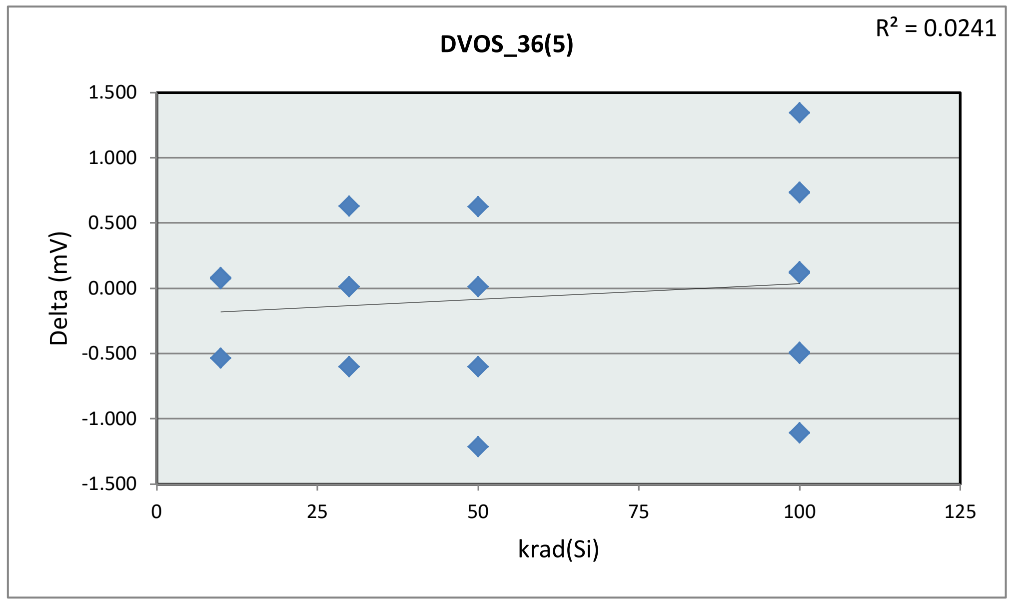


	VOSL_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.170	1.170	1.158	1.167
Average	1.183	1.176	1.171	1.183
Max	1.197	1.183	1.178	1.201
UL	1.450	1.450	1.450	1.450

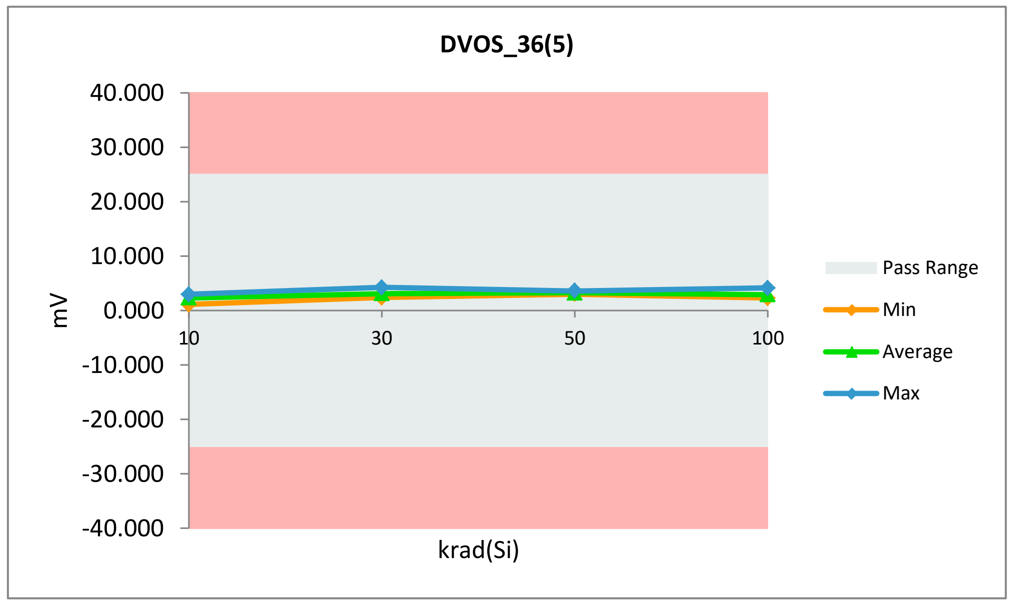


HDR Biased TID Report
SN55LVCP22A-SP

		DVOS_36(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.823	2.360	-0.537
10	2	3.050	2.970	0.080
10	3	1.209	1.138	0.071
10	4	3.050	2.971	0.079
10	5	2.437	2.361	0.076
30	1	3.026	3.628	-0.602
30	2	2.413	2.402	0.011
30	3	3.640	4.242	-0.602
30	4	3.639	3.013	0.626
30	5	2.412	2.400	0.012
50	11	3.027	3.015	0.012
50	12	3.640	3.016	0.624
50	13	3.027	3.628	-0.601
50	14	2.413	3.629	-1.216
50	15	2.413	3.015	-0.602
100	22	2.437	2.321	0.116
100	23	2.437	3.544	-1.107
100	24	3.664	2.320	1.344
100	25	3.050	2.932	0.118
100	26	3.050	2.932	0.118
100	27	3.664	3.543	0.121
100	28	4.277	4.153	0.124
100	29	1.823	2.932	-1.109
100	30	2.436	2.929	-0.493
100	31	3.664	2.930	0.734
100	32	3.664	2.932	0.732
100	33	3.664	2.934	0.730
100	34	3.664	2.931	0.733
100	35	2.436	2.930	-0.494
100	36	3.050	2.933	0.117
100	37	2.437	2.931	-0.494
100	38	2.437	2.321	0.116
100	39	3.050	2.930	0.120
100	41	3.664	3.543	0.121
100	42	1.823	2.323	-0.500
100	43	3.050	2.932	0.118
100	44	2.437	2.320	0.117
	Max	4.277	4.242	1.344
	Average	2.894	2.927	-0.032
	Min	1.209	1.138	-1.216
	Std Dev	0.684	0.580	0.566

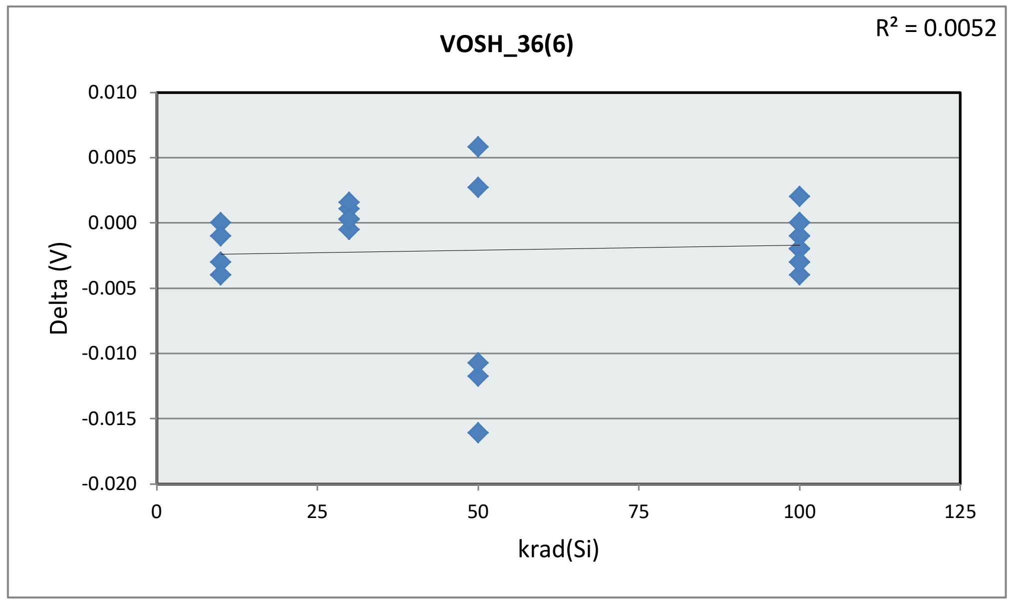


	DVOS_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	1.138	2.400	3.015	2.320
Average	2.360	3.137	3.261	2.932
Max	2.971	4.242	3.629	4.153
UL	25.000	25.000	25.000	25.000

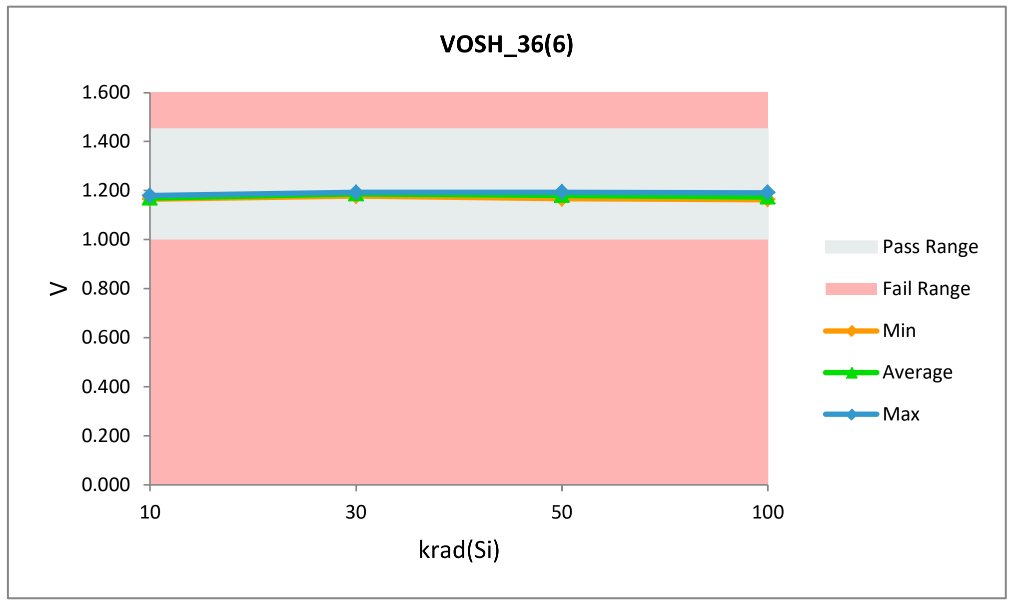


HDR Biased TID Report
SN55LVCP22A-SP

		VOSH_36(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W an	Delta
10	1	1.161	1.165	-0.004
10	2	1.169	1.169	0.000
10	3	1.167	1.168	-0.001
10	4	1.176	1.179	-0.003
10	5	1.162	1.166	-0.004
30	1	1.192	1.191	0.001
30	2	1.179	1.177	0.002
30	3	1.191	1.192	-0.001
30	4	1.182	1.182	0.000
30	5	1.193	1.193	0.000
50	11	1.182	1.194	-0.012
50	12	1.185	1.182	0.003
50	13	1.174	1.185	-0.011
50	14	1.172	1.166	0.006
50	15	1.159	1.175	-0.016
100	22	1.169	1.169	0.000
100	23	1.174	1.175	-0.001
100	24	1.172	1.175	-0.003
100	25	1.177	1.179	-0.002
100	26	1.172	1.174	-0.002
100	27	1.176	1.179	-0.003
100	28	1.175	1.177	-0.002
100	29	1.173	1.174	-0.001
100	30	1.164	1.164	0.000
100	31	1.179	1.177	0.002
100	32	1.175	1.178	-0.003
100	33	1.170	1.174	-0.004
100	34	1.165	1.166	-0.001
100	35	1.191	1.192	-0.001
100	36	1.163	1.163	0.000
100	37	1.165	1.167	-0.002
100	38	1.169	1.169	0.000
100	39	1.186	1.186	0.000
100	41	1.183	1.185	-0.002
100	42	1.173	1.175	-0.002
100	43	1.167	1.169	-0.002
100	44	1.168	1.171	-0.003
	Max	1.193	1.194	0.006
	Average	1.174	1.176	-0.002
	Min	1.159	1.163	-0.016
	Std Dev	0.009	0.009	0.004

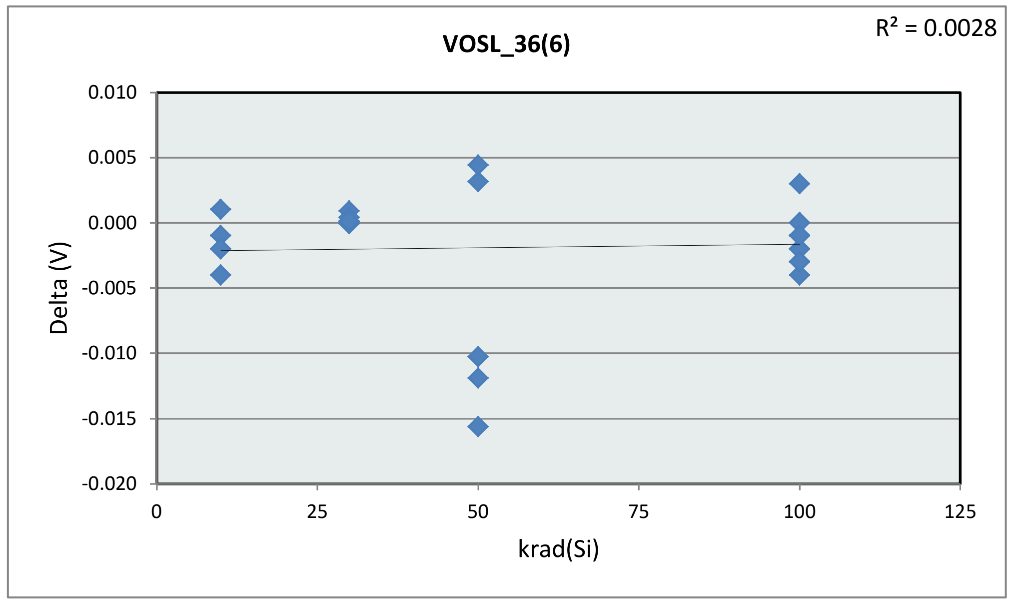


	VOSH_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.165	1.177	1.166	1.163
Average	1.169	1.187	1.180	1.174
Max	1.179	1.193	1.194	1.192
UL	1.450	1.450	1.450	1.450

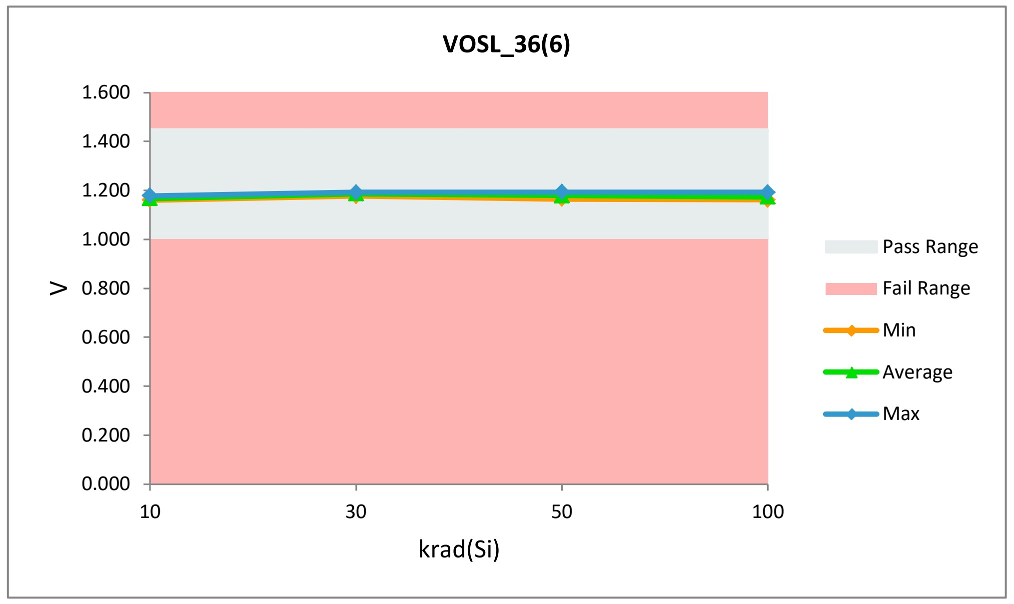


HDR Biased TID Report
SN55LVCP22A-SP

		VOSL_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ani	Delta
10	1	1.159	1.163	-0.004
10	2	1.167	1.169	-0.002
10	3	1.166	1.167	-0.001
10	4	1.176	1.178	-0.002
10	5	1.161	1.160	0.001
30	1	1.191	1.190	0.001
30	2	1.177	1.177	0.000
30	3	1.191	1.191	0.000
30	4	1.181	1.181	0.000
30	5	1.192	1.192	0.000
50	11	1.181	1.193	-0.012
50	12	1.184	1.181	0.003
50	13	1.174	1.184	-0.010
50	14	1.169	1.165	0.004
50	15	1.158	1.174	-0.016
100	22	1.168	1.168	0.000
100	23	1.174	1.174	0.000
100	24	1.171	1.173	-0.002
100	25	1.177	1.178	-0.001
100	26	1.170	1.171	-0.001
100	27	1.176	1.178	-0.002
100	28	1.174	1.176	-0.002
100	29	1.173	1.173	0.000
100	30	1.162	1.163	-0.001
100	31	1.178	1.175	0.003
100	32	1.175	1.178	-0.003
100	33	1.169	1.173	-0.004
100	34	1.164	1.165	-0.001
100	35	1.190	1.192	-0.002
100	36	1.162	1.162	0.000
100	37	1.164	1.166	-0.002
100	38	1.167	1.168	-0.001
100	39	1.184	1.184	0.000
100	41	1.181	1.184	-0.003
100	42	1.172	1.175	-0.003
100	43	1.167	1.168	-0.001
100	44	1.167	1.170	-0.003
	Max	1.192	1.193	0.004
	Average	1.173	1.175	-0.002
	Min	1.158	1.160	-0.016
	Std Dev	0.009	0.009	0.004

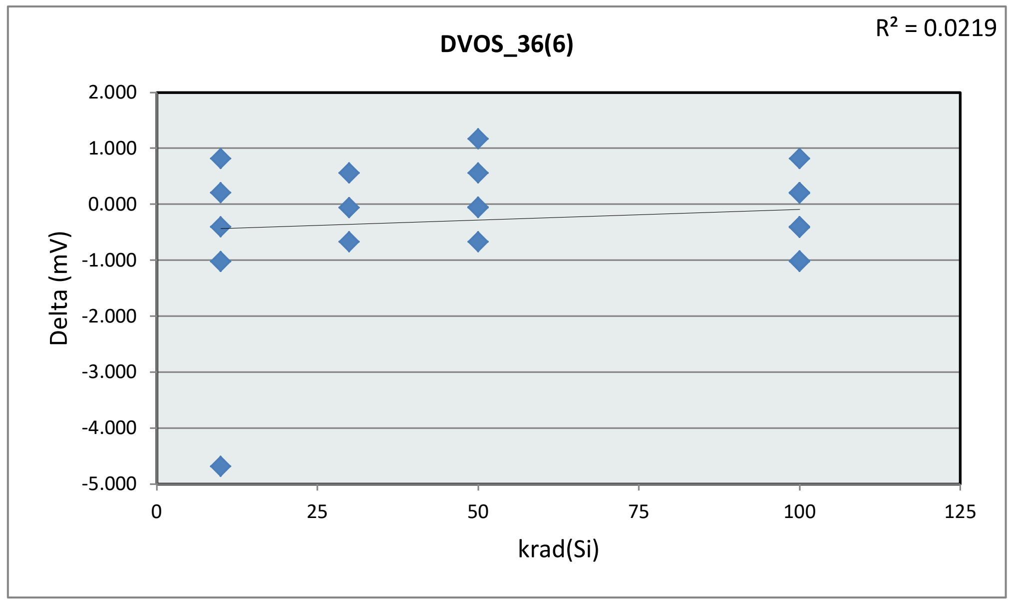


	VOSL_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.160	1.177	1.165	1.162
Average	1.167	1.186	1.179	1.173
Max	1.178	1.192	1.193	1.192
UL	1.450	1.450	1.450	1.450

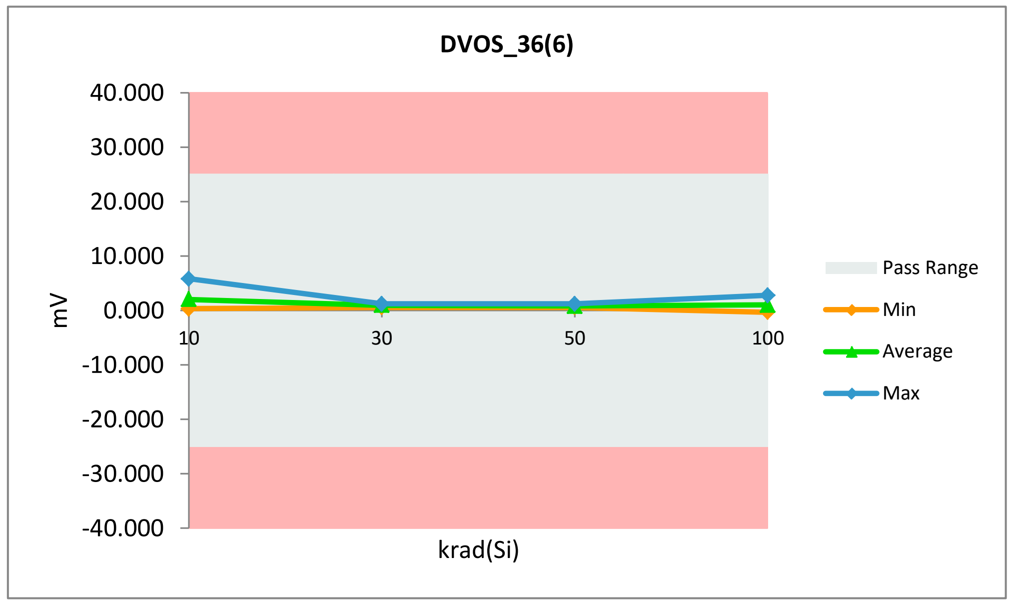


HDR Biased TID Report
SN55LVCP22A-SP

		DVOS_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	SN55 Pre Test	Post Test (3W ann	Delta
10	1	1.751	1.549	0.202
10	2	1.136	0.324	0.812
10	3	1.136	1.546	-0.410
10	4	-0.090	0.942	-1.031
10	5	1.136	5.828	-4.692
30	1	1.164	0.611	0.553
30	2	1.167	0.611	0.556
30	3	0.550	1.225	-0.675
30	4	1.164	1.225	-0.061
30	5	1.164	1.225	-0.061
50	11	1.166	0.611	0.555
50	12	0.550	1.225	-0.675
50	13	0.552	0.611	-0.059
50	14	2.395	1.225	1.170
50	15	0.552	0.611	-0.059
100	22	1.136	0.934	0.202
100	23	0.526	0.943	-0.418
100	24	1.137	1.544	-0.407
100	25	0.522	0.931	-0.409
100	26	1.751	2.770	-1.019
100	27	0.522	0.932	-0.410
100	28	1.136	0.934	0.202
100	29	-0.091	0.934	-1.025
100	30	1.749	1.542	0.207
100	31	1.136	1.543	-0.407
100	32	0.523	0.323	0.200
100	33	0.527	0.946	-0.419
100	34	0.522	0.932	-0.410
100	35	0.520	-0.296	0.816
100	36	1.137	0.325	0.812
100	37	1.137	0.937	0.200
100	38	1.140	0.945	0.195
100	39	1.748	2.761	-1.013
100	41	1.135	0.930	0.205
100	42	0.523	0.324	0.199
100	43	0.522	0.931	-0.409
100	44	0.522	0.932	-0.410
	Max	2.395	5.828	1.170
	Average	0.945	1.145	-0.200
	Min	-0.091	-0.296	-4.692
	Std Dev	0.524	0.983	0.942



	DVOS_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.324	0.611	0.611	-0.296
Average	2.038	0.980	0.857	1.045
Max	5.828	1.225	1.225	2.770
UL	25.000	25.000	25.000	25.000



Delta Threshold	10.00%

HDR UnBiased TID Report
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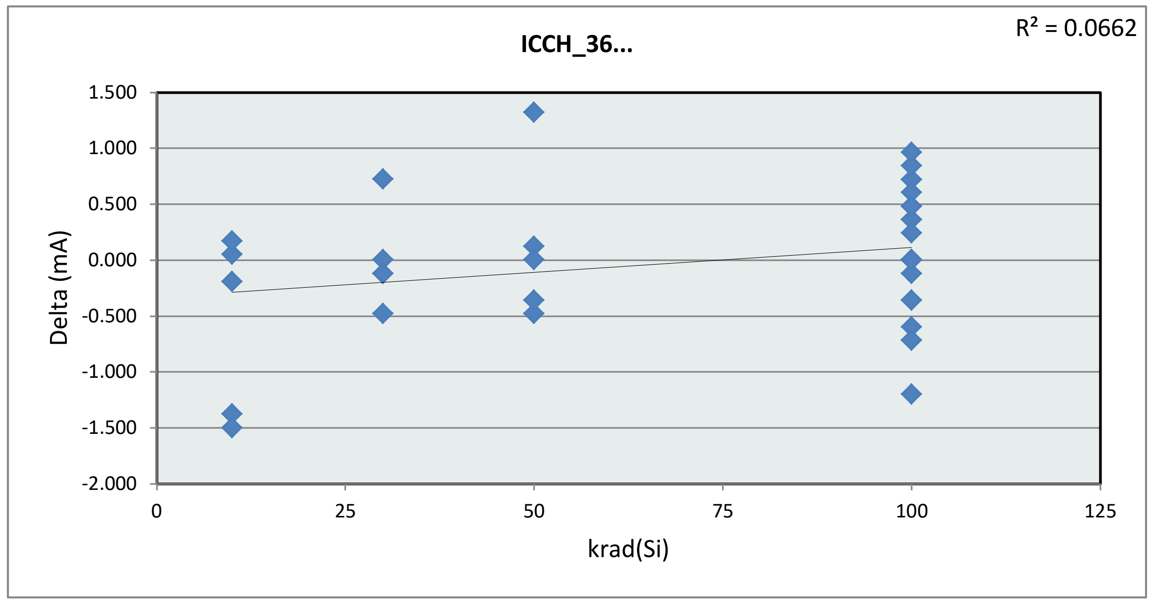
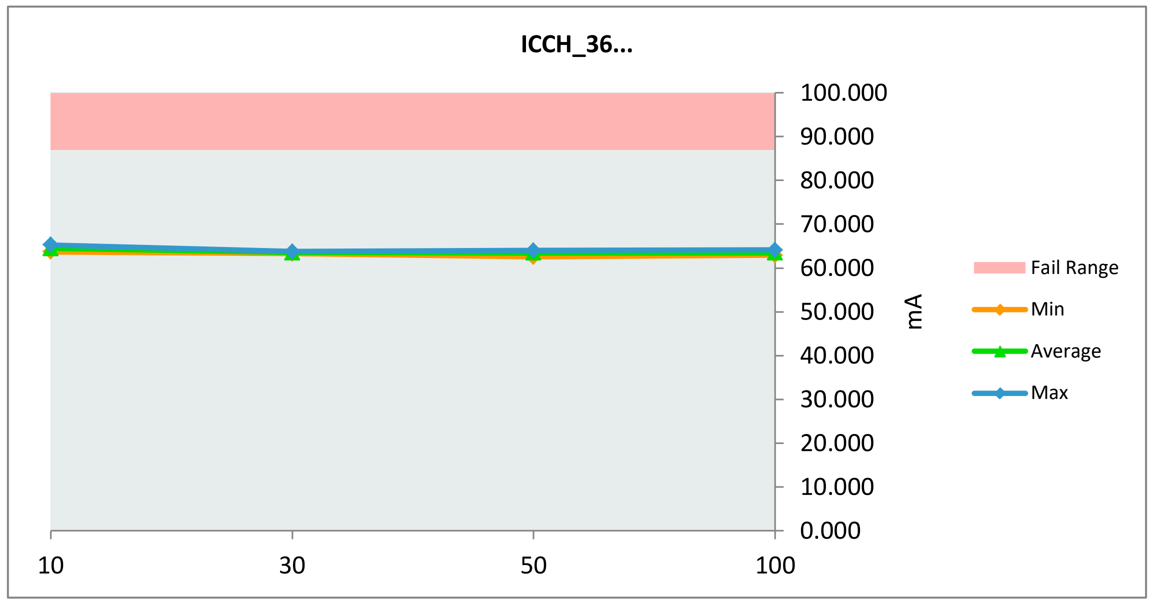
		ICCH_36...		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	87	87	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	64.237	64.184	0.053
10	7	63.877	65.254	-1.377
10	8	63.637	65.135	-1.498
10	9	63.517	63.709	-0.192
10	10	64.357	64.184	0.173
30	6	63.397	63.515	-0.118
30	7	63.397	63.395	0.002
30	8	63.637	63.756	-0.119
30	9	63.157	63.635	-0.478
30	10	63.997	63.275	0.722
50	16	62.676	62.555	0.121
50	17	63.997	63.996	0.001
50	18	64.117	62.795	1.322
50	19	63.517	63.996	-0.479
50	20	63.637	63.996	-0.359
100	B043	63.637	63.635	0.002
100	B044	63.037	63.635	-0.598
100	B045	63.637	62.915	0.722
100	B046	62.917	63.635	-0.718
100	B047	63.397	62.915	0.482
100	B048	63.997	63.635	0.362
100	B049	62.917	64.116	-1.199
100	B050	63.637	62.915	0.722
100	B051	63.757	63.395	0.362
100	B052	63.277	63.996	-0.719
100	B053	63.757	62.915	0.842
100	B054	63.637	63.635	0.002
100	B055	63.757	63.756	0.001
100	B056	63.037	63.395	-0.358
100	B057	63.637	63.635	0.002
100	B058	63.397	63.515	-0.118
100	B059	63.397	63.756	-0.359
100	B060	63.277	63.035	0.242
100	B061	64.478	63.515	0.963
100	B062	63.997	63.390	0.607
100	B063	63.397	63.395	0.002
100	B064	63.757	63.275	0.482
	Max	64.478	65.254	1.322
	Average	63.592	63.605	-0.014
	Min	62.676	62.555	-1.498
	Std Dev	0.406	0.556	0.624

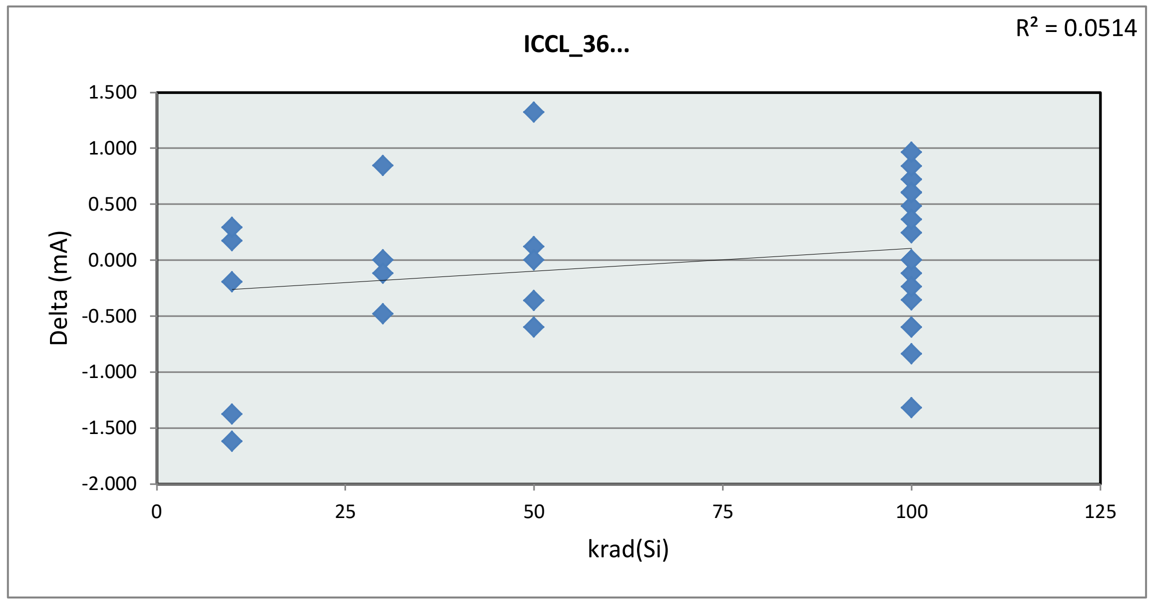


	ICCH_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	63.709	63.275	62.555	62.915
Average	64.493	63.515	63.468	63.455
Max	65.254	63.756	63.996	64.116
UL	87.000	87.000	87.000	87.000

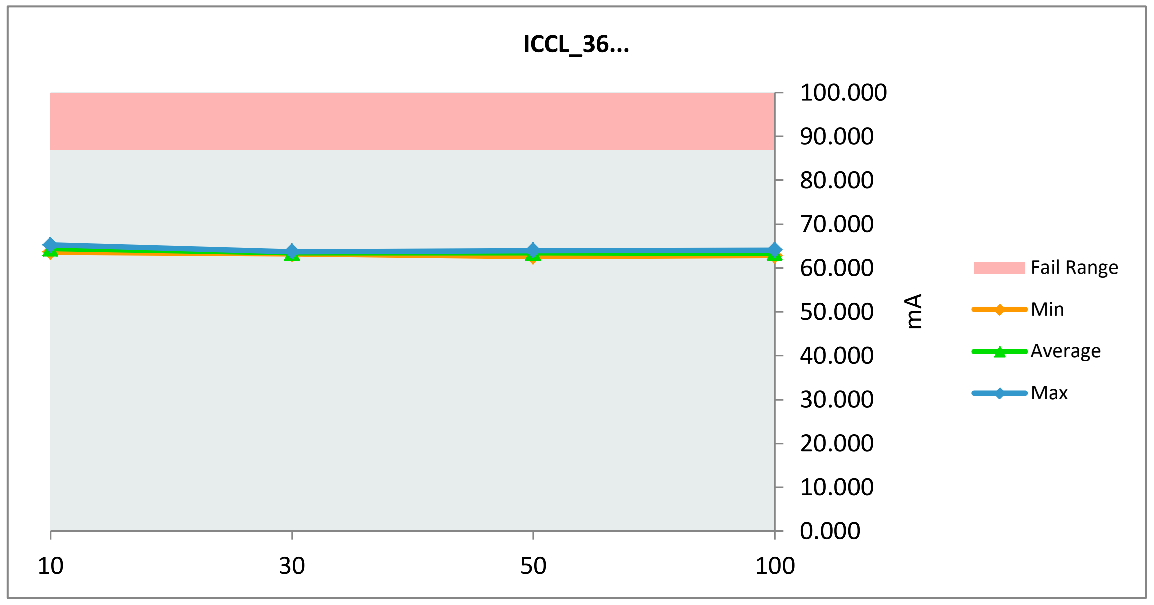


HDR UnBiased TID Report
SN55LVCP22A-SP

		ICCL_36...		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	87	87	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	64.237	64.066	0.171
10	7	63.877	65.254	-1.377
10	8	63.517	65.135	-1.618
10	9	63.397	63.590	-0.193
10	10	64.357	64.066	0.291
30	6	63.397	63.395	0.002
30	7	63.277	63.275	0.002
30	8	63.637	63.756	-0.119
30	9	63.157	63.635	-0.478
30	10	63.997	63.155	0.842
50	16	62.676	62.555	0.121
50	17	63.877	63.876	0.001
50	18	63.997	62.675	1.322
50	19	63.397	63.996	-0.599
50	20	63.637	63.996	-0.359
100	B043	63.637	63.635	0.002
100	B044	62.917	63.515	-0.598
100	B045	63.637	62.915	0.722
100	B046	62.797	63.635	-0.838
100	B047	63.397	62.915	0.482
100	B048	63.877	63.635	0.242
100	B049	62.797	64.116	-1.319
100	B050	63.517	62.795	0.722
100	B051	63.637	63.395	0.242
100	B052	63.277	63.876	-0.599
100	B053	63.637	62.795	0.842
100	B054	63.517	63.515	0.002
100	B055	63.637	63.635	0.002
100	B056	62.917	63.275	-0.358
100	B057	63.517	63.635	-0.118
100	B058	63.397	63.515	-0.118
100	B059	63.397	63.635	-0.238
100	B060	63.277	62.915	0.362
100	B061	64.478	63.515	0.963
100	B062	63.997	63.390	0.607
100	B063	63.277	63.275	0.002
100	B064	63.757	63.155	0.602
	Max	64.478	65.254	1.322
	Average	63.533	63.544	-0.010
	Min	62.676	62.555	-1.618
	Std Dev	0.418	0.570	0.648



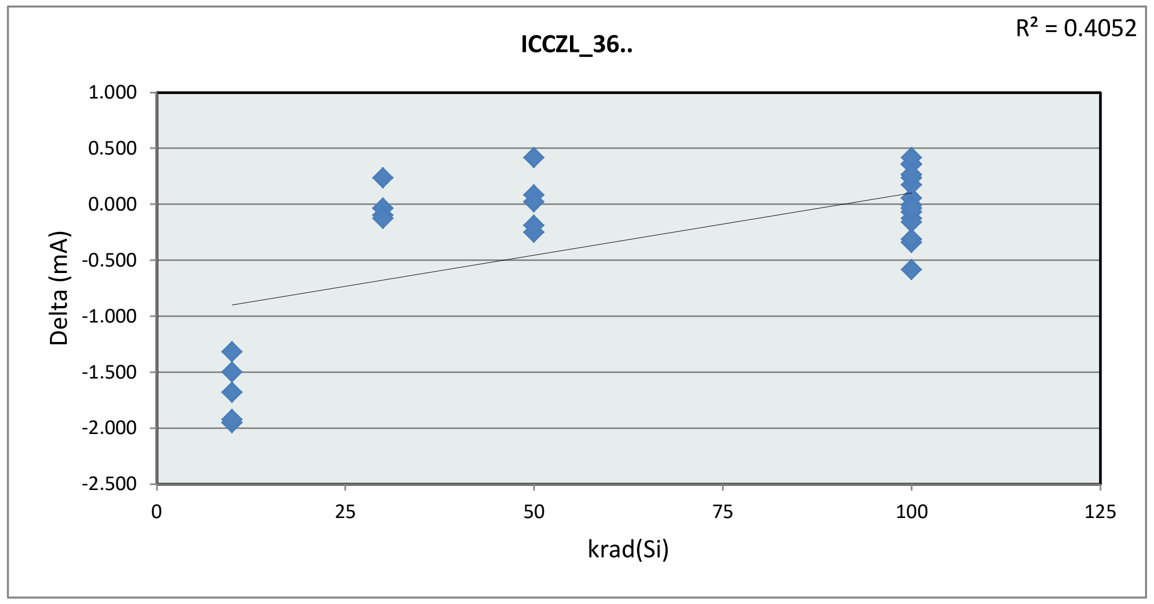
	ICCL_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	63.590	63.155	62.555	62.795
Average	64.422	63.443	63.420	63.395
Max	65.254	63.756	63.996	64.116
UL	87.000	87.000	87.000	87.000



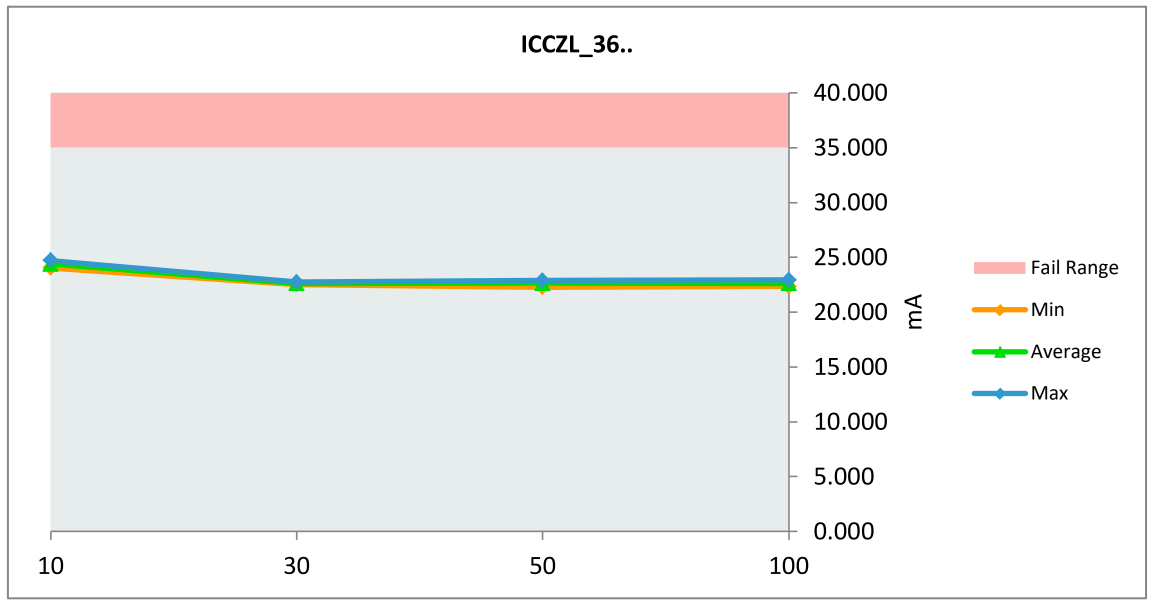
HDR UnBiased TID Report
SN55LVCP22A-SP

	ICCZL_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	22.677	24.358	-1.681
10	7	22.768	24.720	-1.952
10	8	22.677	24.599	-1.922
10	9	22.525	24.026	-1.501
10	10	22.920	24.237	-1.317
30	6	22.578	22.616	-0.038
30	7	22.487	22.525	-0.038
30	8	22.639	22.738	-0.099
30	9	22.518	22.647	-0.129
30	10	22.760	22.525	0.235
50	16	22.366	22.282	0.084
50	17	22.882	22.859	0.023
50	18	22.791	22.373	0.418
50	19	22.639	22.889	-0.250
50	20	22.609	22.798	-0.189
100	B043	22.669	22.738	-0.069
100	B044	22.366	22.707	-0.341
100	B045	22.760	22.404	0.356
100	B046	22.366	22.707	-0.341
100	B047	22.700	22.343	0.357
100	B048	22.851	22.798	0.053
100	B049	22.366	22.950	-0.584
100	B050	22.730	22.373	0.357
100	B051	22.669	22.707	-0.038
100	B052	22.518	22.829	-0.311
100	B053	22.760	22.343	0.417
100	B054	22.609	22.738	-0.129
100	B055	22.700	22.647	0.053
100	B056	22.366	22.525	-0.159
100	B057	22.730	22.738	-0.008
100	B058	22.609	22.616	-0.007
100	B059	22.609	22.677	-0.068
100	B060	22.548	22.373	0.175
100	B061	23.003	22.738	0.265
100	B062	22.851	22.616	0.236
100	B063	22.578	22.616	-0.038
100	B064	22.821	22.556	0.265
	Max	23.003	24.720	0.418
	Average	22.649	22.863	-0.214
	Min	22.366	22.282	-1.952
	Std Dev	0.163	0.640	0.635



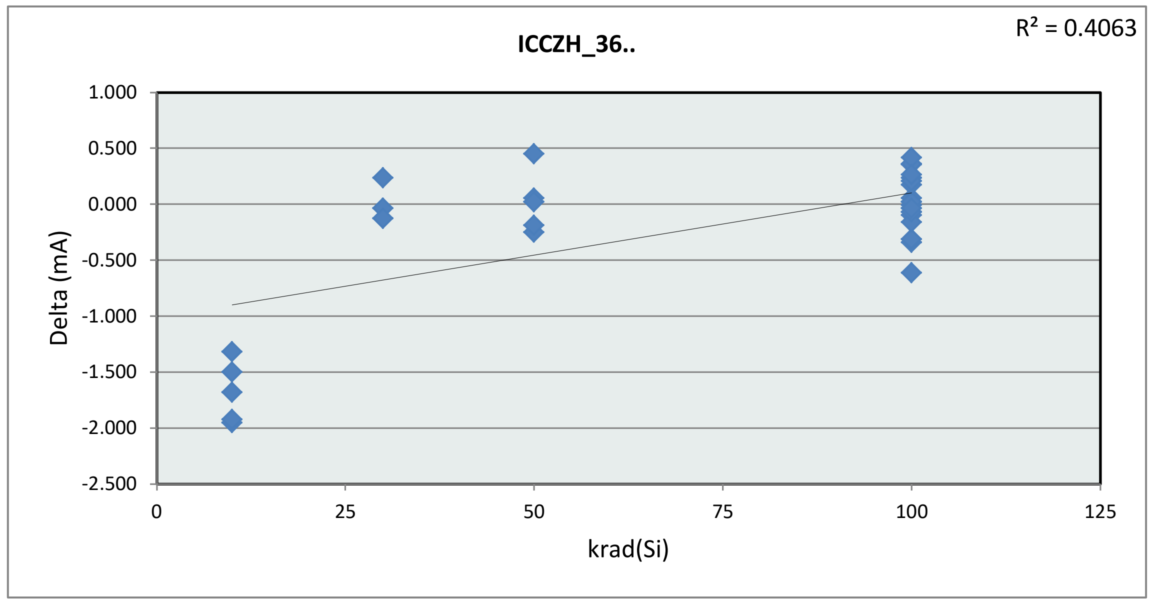
	ICCZL_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	24.026	22.525	22.282	22.343
Average	24.388	22.610	22.640	22.625
Max	24.720	22.738	22.889	22.950
UL	35.000	35.000	35.000	35.000



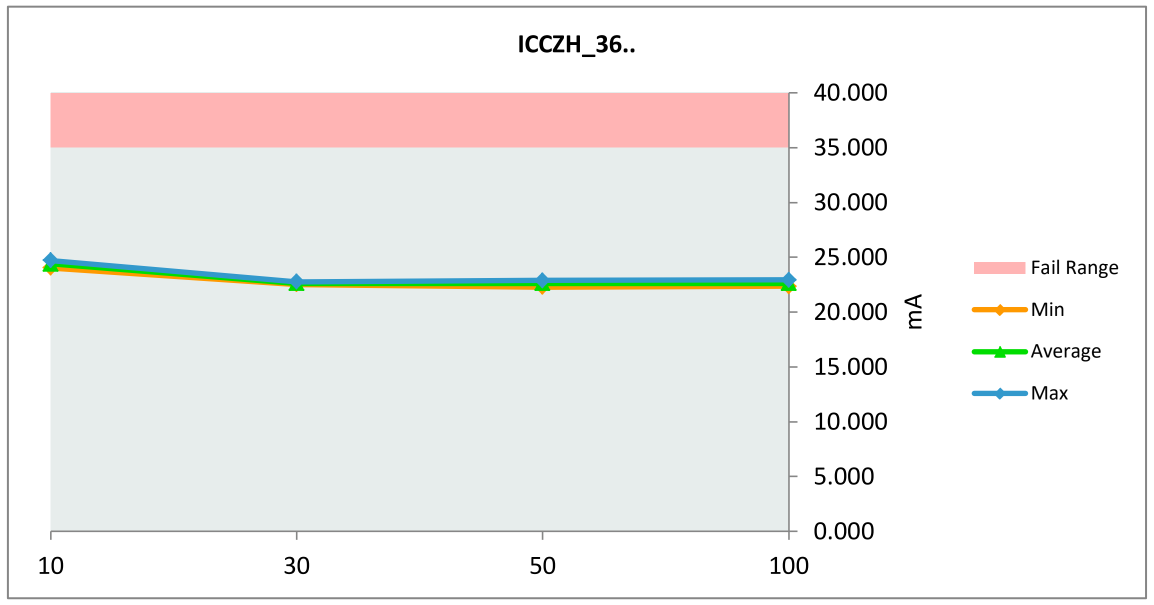
HDR UnBiased TID Report
SN55LVCP22A-SP

	ICCZH_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	22.677	24.358	-1.681
10	7	22.768	24.720	-1.952
10	8	22.677	24.599	-1.922
10	9	22.525	24.026	-1.501
10	10	22.920	24.237	-1.317
30	6	22.578	22.616	-0.038
30	7	22.487	22.525	-0.038
30	8	22.639	22.768	-0.129
30	9	22.518	22.647	-0.129
30	10	22.760	22.525	0.235
50	16	22.336	22.282	0.054
50	17	22.851	22.829	0.022
50	18	22.791	22.343	0.448
50	19	22.639	22.889	-0.250
50	20	22.609	22.798	-0.189
100	B043	22.669	22.738	-0.069
100	B044	22.366	22.707	-0.341
100	B045	22.760	22.404	0.356
100	B046	22.366	22.677	-0.311
100	B047	22.700	22.343	0.357
100	B048	22.851	22.798	0.053
100	B049	22.336	22.950	-0.614
100	B050	22.730	22.373	0.357
100	B051	22.669	22.707	-0.038
100	B052	22.518	22.829	-0.311
100	B053	22.760	22.343	0.417
100	B054	22.609	22.707	-0.098
100	B055	22.669	22.647	0.022
100	B056	22.366	22.525	-0.159
100	B057	22.730	22.738	-0.008
100	B058	22.609	22.586	0.023
100	B059	22.609	22.677	-0.068
100	B060	22.548	22.373	0.175
100	B061	22.973	22.738	0.235
100	B062	22.821	22.616	0.205
100	B063	22.578	22.616	-0.038
100	B064	22.821	22.556	0.265
	Max	22.973	24.720	0.448
	Average	22.644	22.860	-0.216
	Min	22.336	22.282	-1.952
	Std Dev	0.162	0.641	0.634

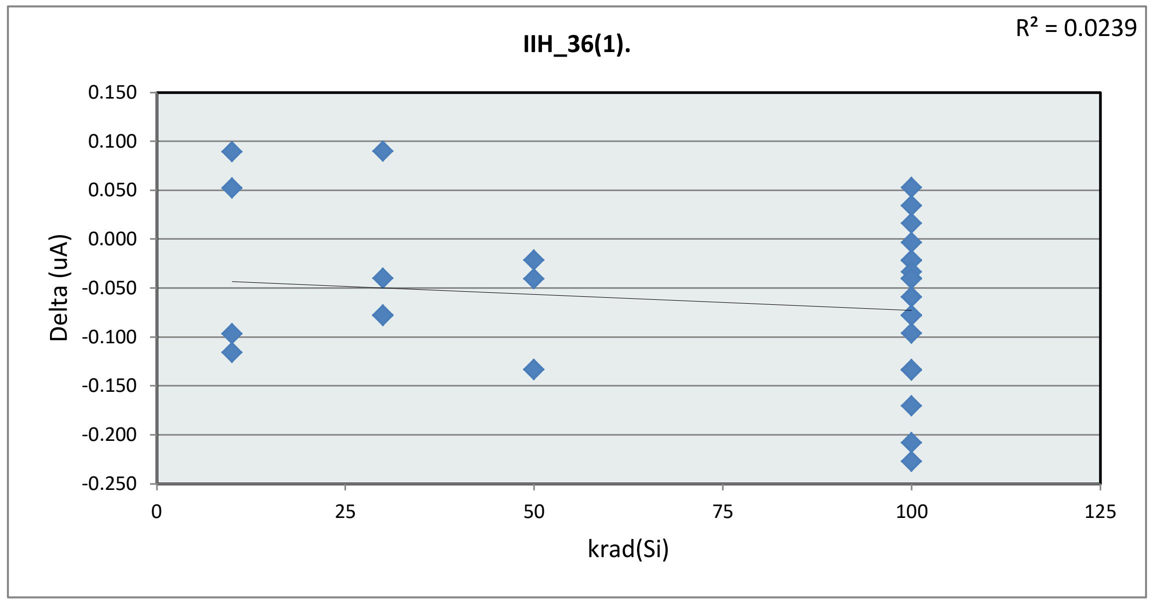


	ICCZH_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	24.026	22.525	22.282	22.343
Average	24.388	22.616	22.628	22.620
Max	24.720	22.768	22.889	22.950
UL	35.000	35.000	35.000	35.000

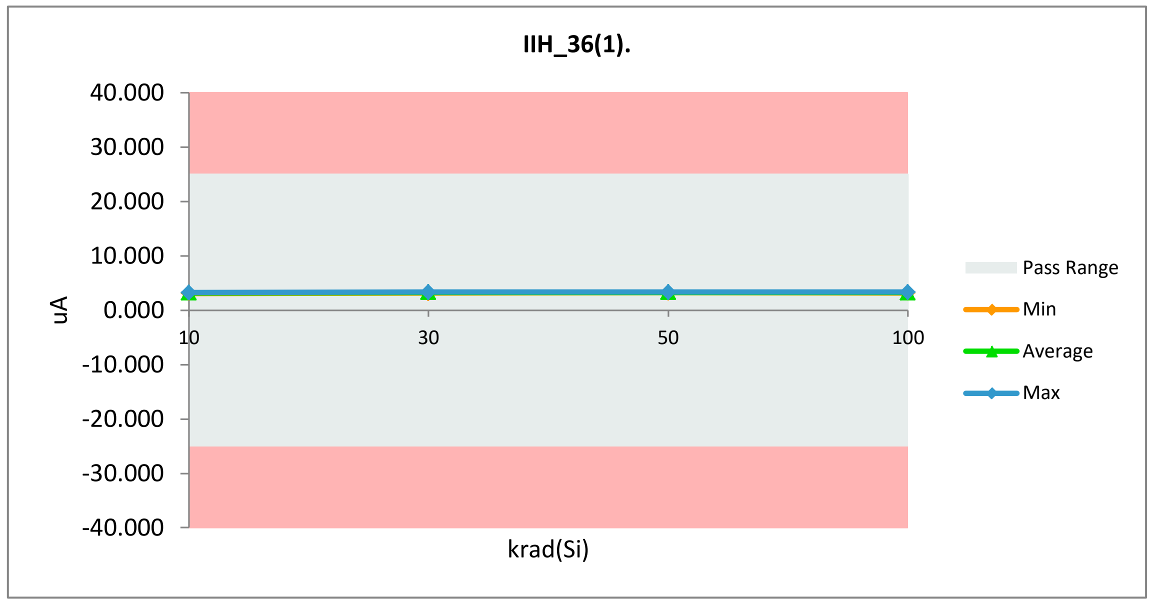


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	3.099	3.215	-0.116
10	7	3.155	3.103	0.052
10	8	3.080	3.177	-0.097
10	9	3.285	3.196	0.089
10	10	3.136	3.233	-0.097
30	6	3.255	3.333	-0.078
30	7	3.274	3.352	-0.078
30	8	3.218	3.128	0.090
30	9	3.218	3.258	-0.040
30	10	3.218	3.296	-0.078
50	16	3.199	3.333	-0.134
50	17	3.199	3.221	-0.022
50	18	3.237	3.277	-0.040
50	19	3.143	3.277	-0.134
50	20	3.181	3.314	-0.133
100	B043	3.181	3.203	-0.022
100	B044	3.255	3.221	0.034
100	B045	3.143	3.240	-0.097
100	B046	3.218	3.258	-0.040
100	B047	3.143	3.314	-0.171
100	B048	3.199	3.221	-0.022
100	B049	3.274	3.258	0.016
100	B050	3.162	3.296	-0.134
100	B051	3.274	3.240	0.034
100	B052	3.218	3.277	-0.059
100	B053	3.125	3.333	-0.208
100	B054	3.237	3.240	-0.003
100	B055	3.274	3.352	-0.078
100	B056	3.218	3.277	-0.059
100	B057	3.106	3.184	-0.078
100	B058	3.162	3.296	-0.134
100	B059	3.125	3.352	-0.227
100	B060	3.143	3.277	-0.134
100	B061	3.237	3.184	0.053
100	B062	3.199	3.233	-0.034
100	B063	3.162	3.203	-0.041
100	B064	3.106	3.240	-0.134
	Max	3.285	3.352	0.090
	Average	3.191	3.254	-0.064
	Min	3.080	3.103	-0.227
	Std Dev	0.057	0.061	0.077

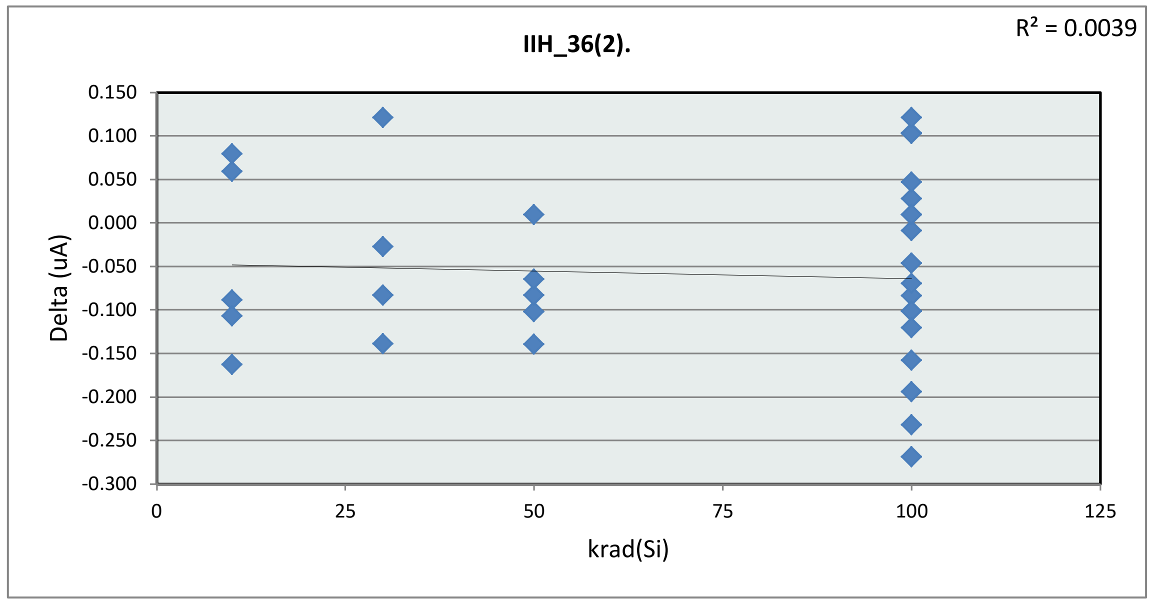


	IIH_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.103	3.128	3.221	3.184
Average	3.185	3.273	3.284	3.259
Max	3.233	3.352	3.333	3.352
UL	25.000	25.000	25.000	25.000

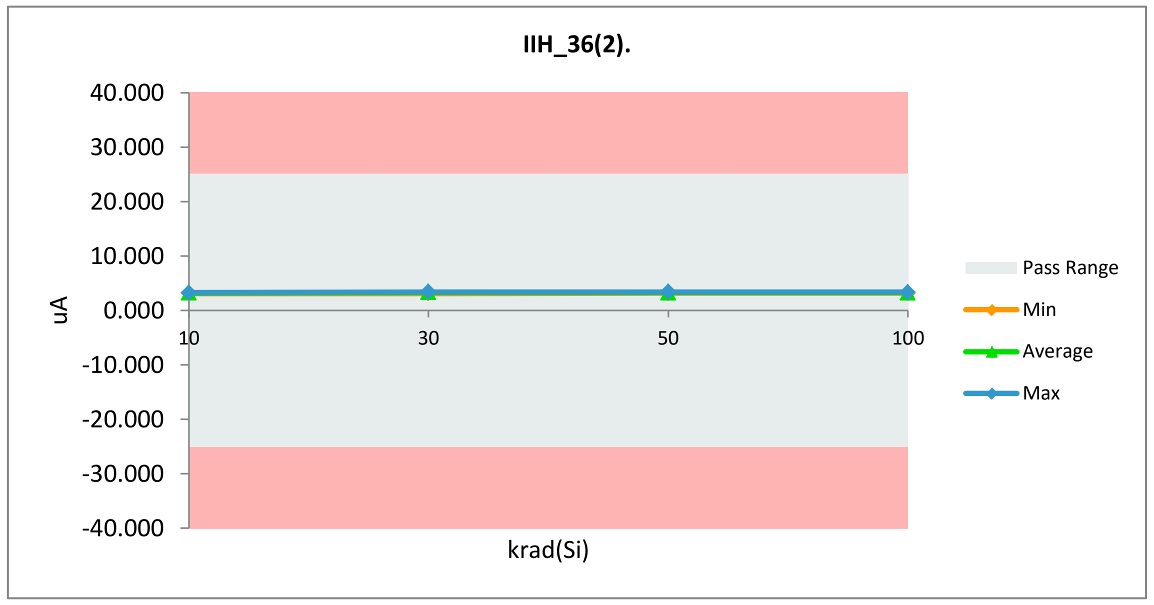


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	3.127	3.290	-0.163
10	7	3.201	3.142	0.059
10	8	3.127	3.216	-0.089
10	9	3.369	3.290	0.079
10	10	3.183	3.290	-0.107
30	6	3.312	3.395	-0.083
30	7	3.349	3.432	-0.083
30	8	3.256	3.135	0.121
30	9	3.275	3.302	-0.027
30	10	3.182	3.321	-0.139
50	16	3.275	3.414	-0.139
50	17	3.200	3.191	0.009
50	18	3.219	3.321	-0.102
50	19	3.182	3.265	-0.083
50	20	3.219	3.284	-0.065
100	B043	3.200	3.191	0.009
100	B044	3.312	3.209	0.103
100	B045	3.163	3.265	-0.102
100	B046	3.256	3.265	-0.009
100	B047	3.126	3.358	-0.232
100	B048	3.182	3.228	-0.046
100	B049	3.330	3.228	0.102
100	B050	3.145	3.339	-0.194
100	B051	3.312	3.191	0.121
100	B052	3.275	3.247	0.028
100	B053	3.126	3.395	-0.269
100	B054	3.275	3.228	0.047
100	B055	3.330	3.377	-0.047
100	B056	3.256	3.358	-0.102
100	B057	3.107	3.191	-0.084
100	B058	3.238	3.339	-0.101
100	B059	3.126	3.395	-0.269
100	B060	3.200	3.321	-0.121
100	B061	3.200	3.191	0.009
100	B062	3.238	3.307	-0.069
100	B063	3.200	3.191	0.009
100	B064	3.126	3.284	-0.158
	Max	3.369	3.432	0.121
	Average	3.222	3.281	-0.059
	Min	3.107	3.135	-0.269
	Std Dev	0.072	0.079	0.102

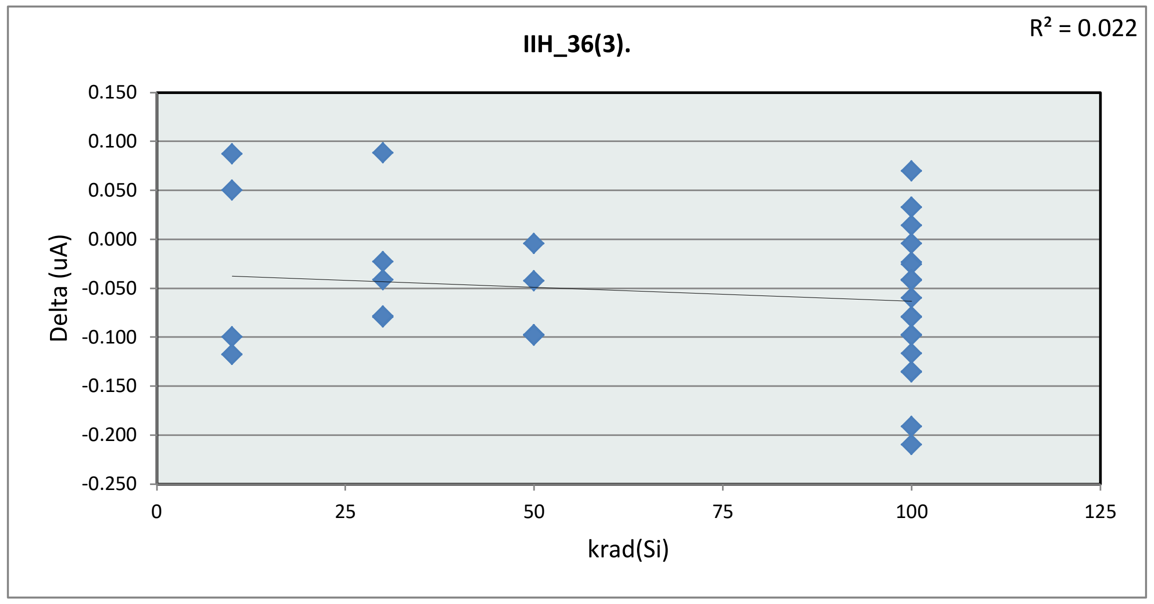


	IIH_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.142	3.135	3.191	3.191
Average	3.246	3.317	3.295	3.277
Max	3.290	3.432	3.414	3.395
UL	25.000	25.000	25.000	25.000

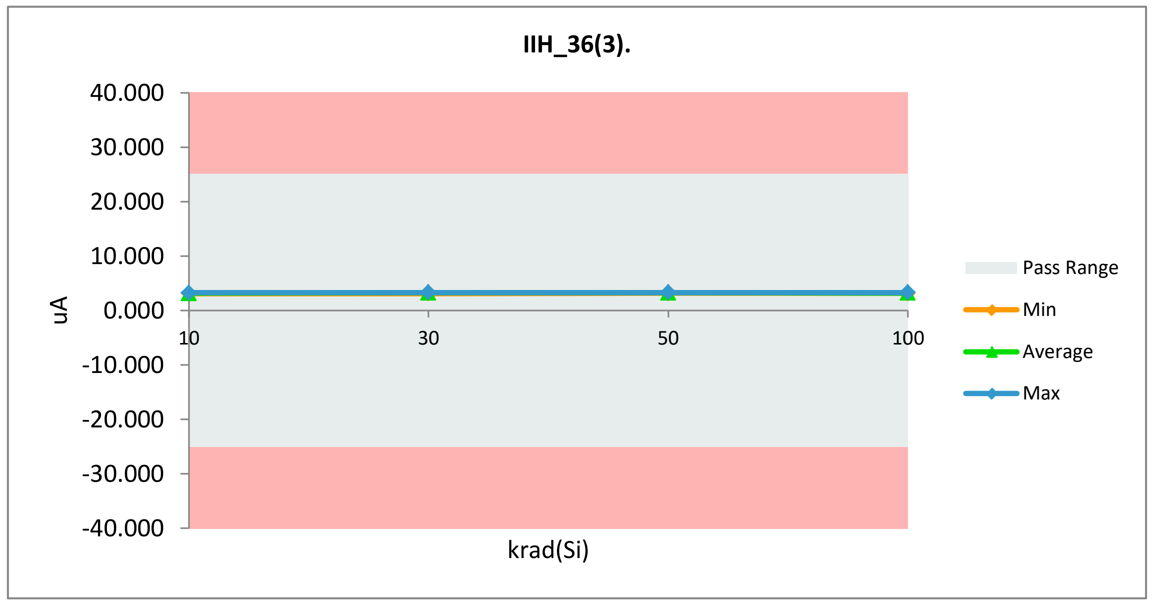


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(3).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	3.103	3.203	-0.100
10	7	3.178	3.128	0.050
10	8	3.085	3.203	-0.118
10	9	3.308	3.221	0.087
10	10	3.159	3.277	-0.118
30	6	3.256	3.335	-0.079
30	7	3.274	3.353	-0.079
30	8	3.218	3.130	0.088
30	9	3.218	3.260	-0.042
30	10	3.237	3.260	-0.023
50	16	3.237	3.335	-0.098
50	17	3.200	3.204	-0.004
50	18	3.256	3.298	-0.042
50	19	3.162	3.260	-0.098
50	20	3.200	3.298	-0.098
100	B043	3.162	3.204	-0.042
100	B044	3.256	3.223	0.033
100	B045	3.162	3.260	-0.098
100	B046	3.218	3.223	-0.005
100	B047	3.162	3.298	-0.136
100	B048	3.200	3.223	-0.023
100	B049	3.274	3.260	0.014
100	B050	3.181	3.279	-0.098
100	B051	3.293	3.223	0.070
100	B052	3.218	3.260	-0.042
100	B053	3.125	3.335	-0.210
100	B054	3.200	3.242	-0.042
100	B055	3.293	3.353	-0.060
100	B056	3.200	3.279	-0.079
100	B057	3.107	3.186	-0.079
100	B058	3.181	3.279	-0.098
100	B059	3.144	3.335	-0.191
100	B060	3.162	3.279	-0.117
100	B061	3.218	3.186	0.032
100	B062	3.218	3.244	-0.026
100	B063	3.162	3.204	-0.042
100	B064	3.088	3.223	-0.135
	Max	3.308	3.353	0.088
	Average	3.198	3.253	-0.055
	Min	3.085	3.128	-0.210
	Std Dev	0.057	0.056	0.071



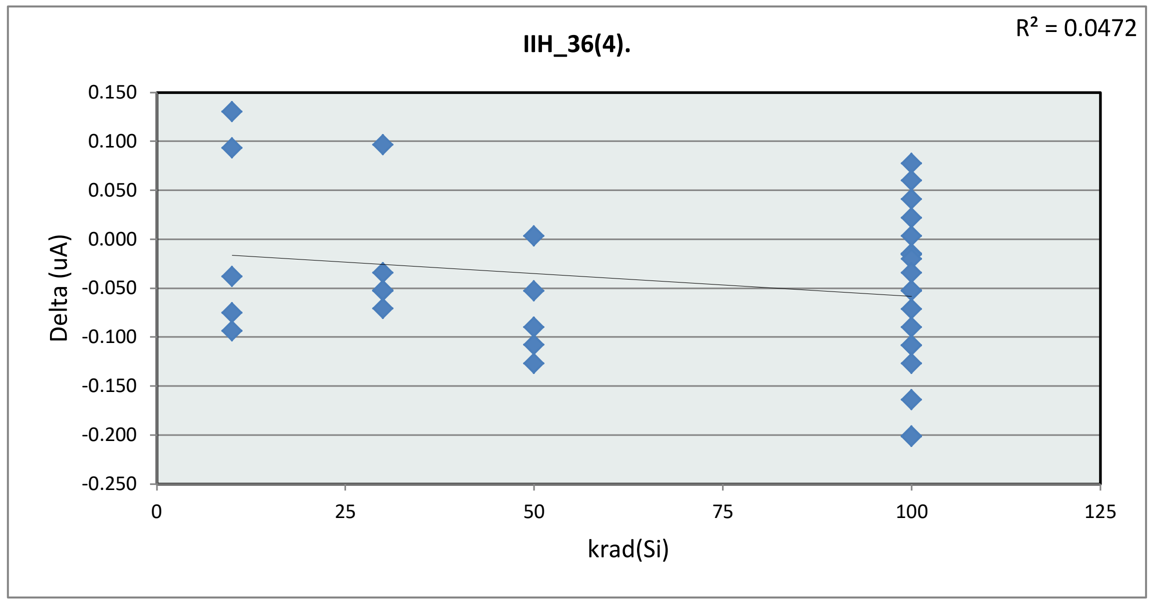
	IIH_36(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.128	3.130	3.204	3.186
Average	3.206	3.268	3.279	3.254
Max	3.277	3.353	3.335	3.353
UL	25.000	25.000	25.000	25.000



HDR UnBiased TID Report
SN55LVCP22A-SP

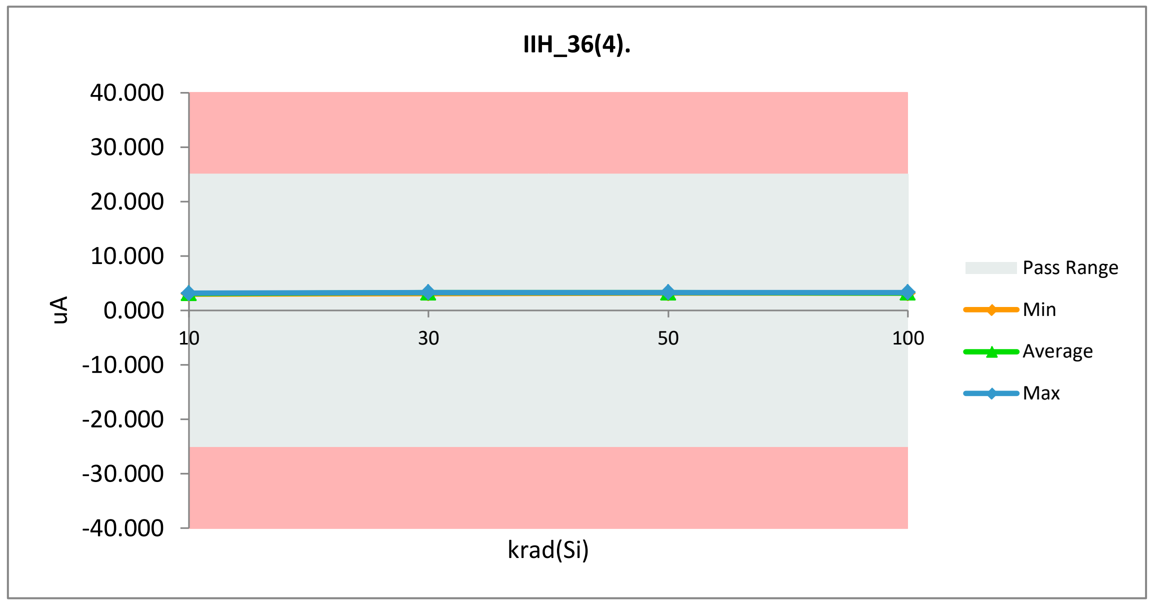
	IIH_36(4).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	3.097	3.172	-0.075
10	7	3.153	3.060	0.093
10	8	3.078	3.172	-0.094
10	9	3.302	3.172	0.130
10	10	3.171	3.209	-0.038
30	6	3.260	3.331	-0.071
30	7	3.297	3.350	-0.053
30	8	3.223	3.126	0.097
30	9	3.223	3.257	-0.034
30	10	3.223	3.275	-0.052
50	16	3.241	3.331	-0.090
50	17	3.204	3.201	0.003
50	18	3.241	3.294	-0.053
50	19	3.148	3.275	-0.127
50	20	3.204	3.312	-0.108
100	B043	3.167	3.182	-0.015
100	B044	3.260	3.219	0.041
100	B045	3.167	3.238	-0.071
100	B046	3.223	3.238	-0.015
100	B047	3.148	3.312	-0.164
100	B048	3.204	3.219	-0.015
100	B049	3.260	3.238	0.022
100	B050	3.185	3.294	-0.109
100	B051	3.278	3.201	0.077
100	B052	3.241	3.257	-0.016
100	B053	3.111	3.312	-0.201
100	B054	3.241	3.238	0.003
100	B055	3.297	3.350	-0.053
100	B056	3.204	3.294	-0.090
100	B057	3.111	3.163	-0.052
100	B058	3.185	3.294	-0.109
100	B059	3.148	3.350	-0.202
100	B060	3.167	3.275	-0.108
100	B061	3.223	3.163	0.060
100	B062	3.223	3.243	-0.020
100	B063	3.167	3.201	-0.034
100	B064	3.111	3.238	-0.127
	Max	3.302	3.350	0.130
	Average	3.200	3.245	-0.045
	Min	3.078	3.060	-0.202
	Std Dev	0.058	0.068	0.078



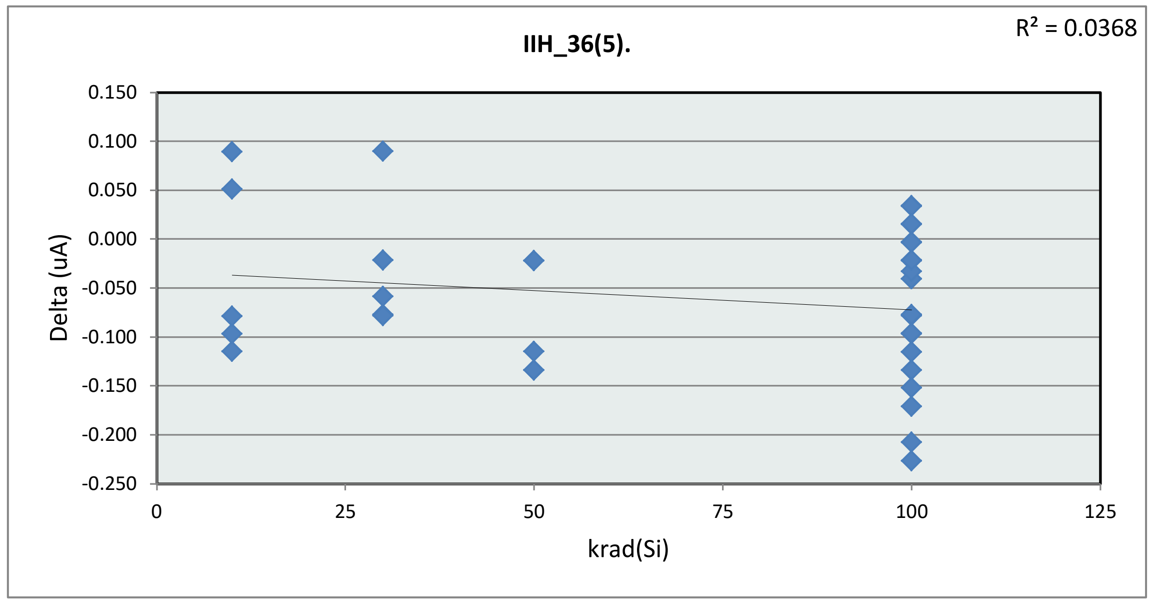
	IIH_36(4).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.060	3.126	3.201	3.163
Average	3.157	3.268	3.283	3.251
Max	3.209	3.350	3.331	3.350
UL	25.000	25.000	25.000	25.000

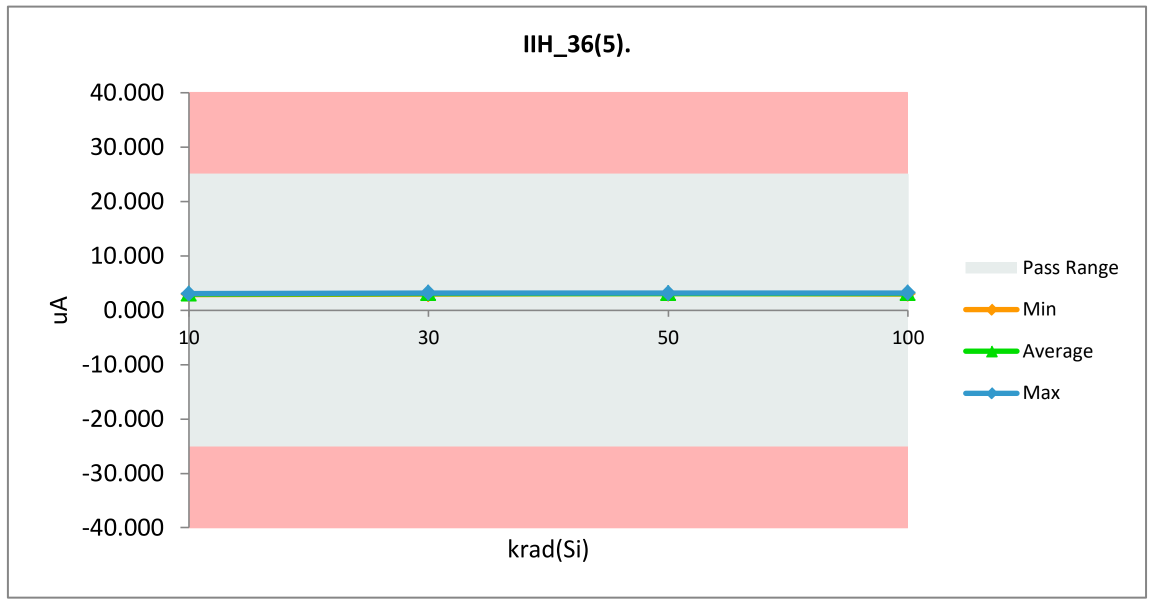


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(5).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	2.913	3.028	-0.115
10	7	2.968	2.917	0.051
10	8	2.894	2.991	-0.097
10	9	3.099	3.010	0.089
10	10	2.968	3.047	-0.079
30	6	3.088	3.165	-0.077
30	7	3.106	3.165	-0.059
30	8	3.032	2.942	0.090
30	9	3.050	3.072	-0.022
30	10	3.032	3.110	-0.078
50	16	3.013	3.147	-0.134
50	17	3.013	3.035	-0.022
50	18	3.069	3.091	-0.022
50	19	2.957	3.091	-0.134
50	20	3.013	3.128	-0.115
100	B043	3.013	3.016	-0.003
100	B044	3.069	3.035	0.034
100	B045	2.957	3.054	-0.097
100	B046	3.032	3.054	-0.022
100	B047	2.957	3.128	-0.171
100	B048	3.013	3.054	-0.041
100	B049	3.069	3.054	0.015
100	B050	2.976	3.110	-0.134
100	B051	3.088	3.054	0.034
100	B052	3.050	3.091	-0.041
100	B053	2.939	3.165	-0.226
100	B054	3.050	3.054	-0.004
100	B055	3.088	3.184	-0.096
100	B056	3.032	3.110	-0.078
100	B057	2.939	3.016	-0.077
100	B058	2.994	3.110	-0.116
100	B059	2.957	3.165	-0.208
100	B060	2.976	3.091	-0.115
100	B061	3.032	3.016	0.016
100	B062	3.013	3.046	-0.033
100	B063	2.994	3.016	-0.022
100	B064	2.920	3.072	-0.152
	Max	3.106	3.184	0.090
	Average	3.010	3.071	-0.061
	Min	2.894	2.917	-0.226
	Std Dev	0.056	0.062	0.076

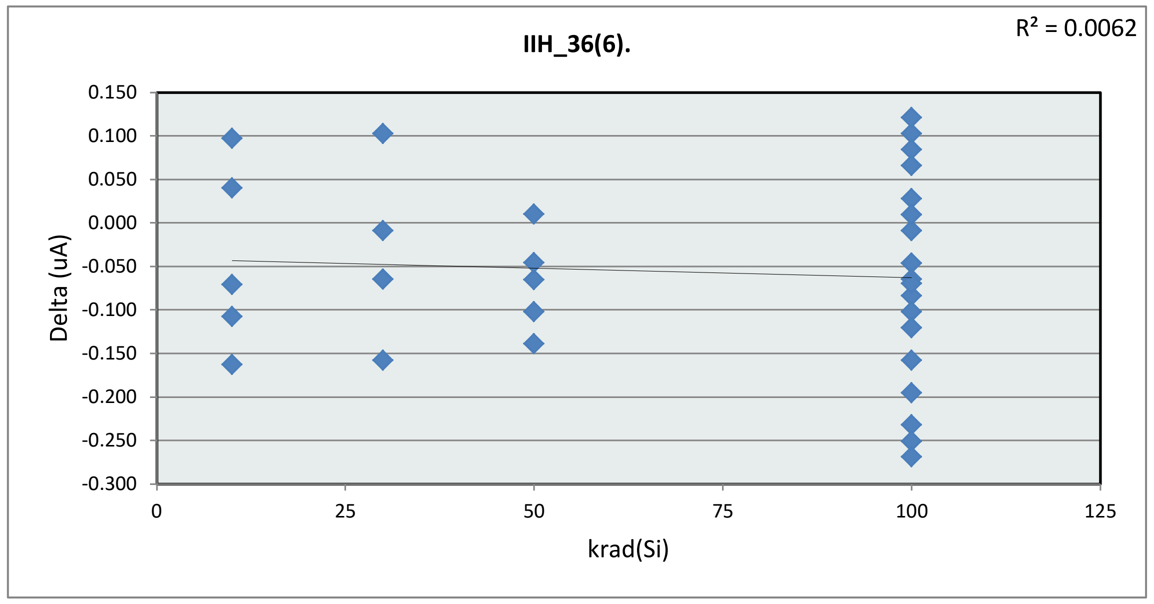


	IIH_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.917	2.942	3.035	3.016
Average	2.999	3.091	3.098	3.077
Max	3.047	3.165	3.147	3.184
UL	25.000	25.000	25.000	25.000

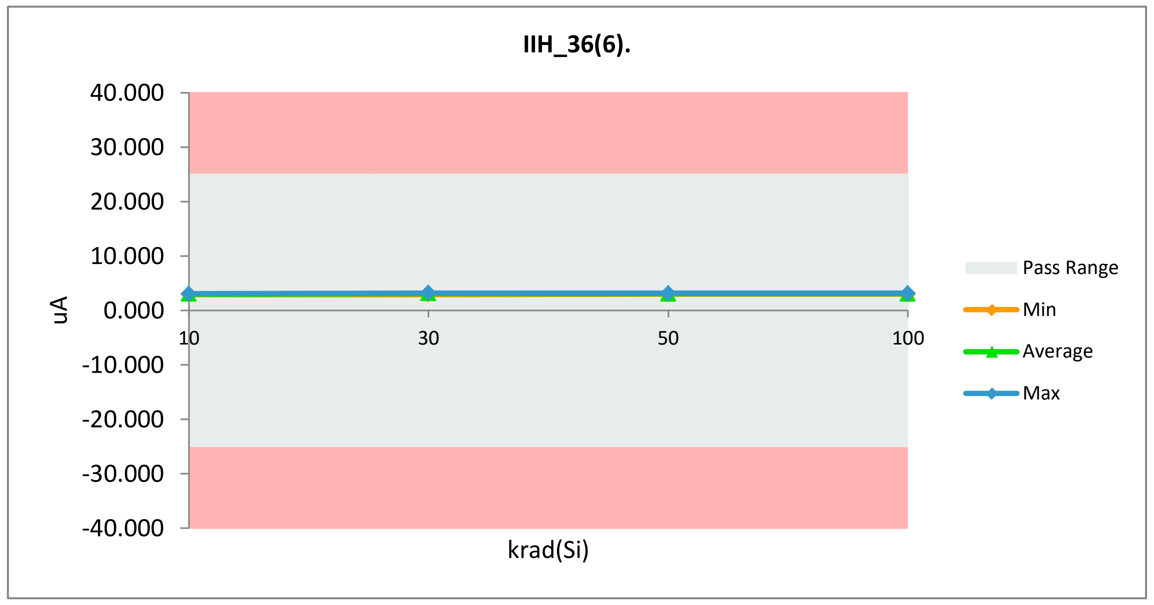


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(6).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	2.923	3.086	-0.163
10	7	2.997	2.957	0.040
10	8	2.941	3.012	-0.071
10	9	3.183	3.086	0.097
10	10	2.997	3.105	-0.108
30	6	3.126	3.191	-0.065
30	7	3.163	3.228	-0.065
30	8	3.052	2.949	0.103
30	9	3.089	3.098	-0.009
30	10	2.977	3.135	-0.158
50	16	3.070	3.209	-0.139
50	17	2.996	2.986	0.010
50	18	3.033	3.135	-0.102
50	19	2.996	3.061	-0.065
50	20	3.033	3.079	-0.046
100	B043	2.996	3.005	-0.009
100	B044	3.107	3.005	0.102
100	B045	2.959	3.079	-0.120
100	B046	3.070	3.061	0.009
100	B047	2.940	3.172	-0.232
100	B048	2.996	3.042	-0.046
100	B049	3.126	3.042	0.084
100	B050	2.959	3.154	-0.195
100	B051	3.126	3.005	0.121
100	B052	3.089	3.061	0.028
100	B053	2.940	3.191	-0.251
100	B054	3.089	3.023	0.066
100	B055	3.145	3.191	-0.046
100	B056	3.070	3.154	-0.084
100	B057	2.940	3.005	-0.065
100	B058	3.033	3.135	-0.102
100	B059	2.940	3.209	-0.269
100	B060	3.014	3.135	-0.121
100	B061	2.996	3.005	-0.009
100	B062	3.033	3.103	-0.070
100	B063	3.014	3.005	0.009
100	B064	2.940	3.098	-0.158
	Max	3.183	3.228	0.121
	Average	3.030	3.086	-0.057
	Min	2.923	2.949	-0.269
	Std Dev	0.072	0.077	0.101

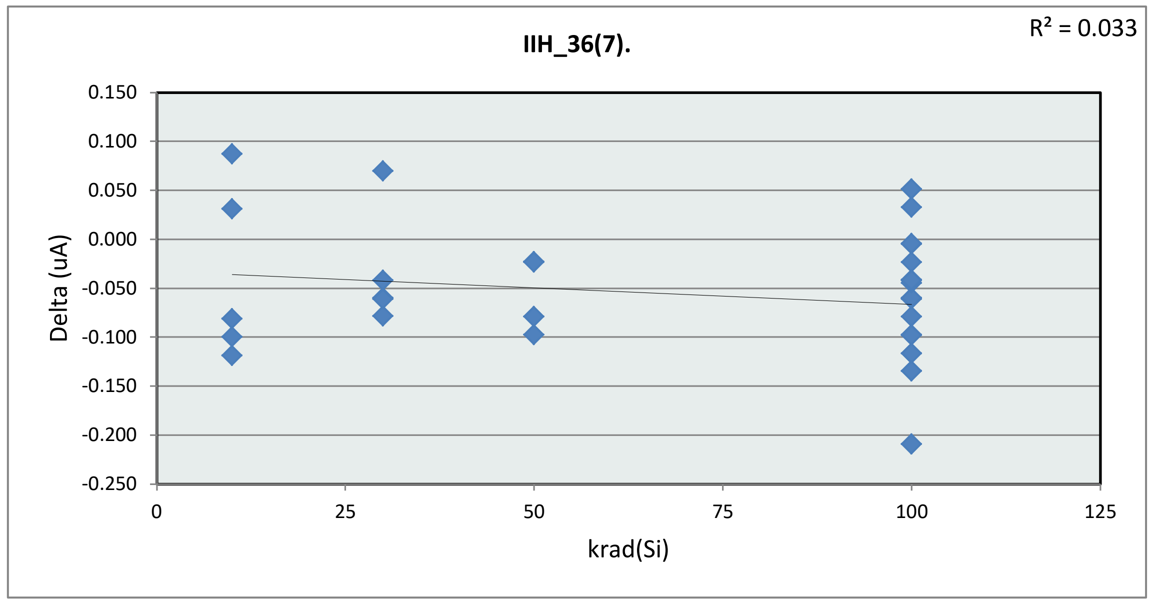


	IIH_36(6).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.957	2.949	2.986	3.005
Average	3.049	3.120	3.094	3.085
Max	3.105	3.228	3.209	3.209
UL	25.000	25.000	25.000	25.000

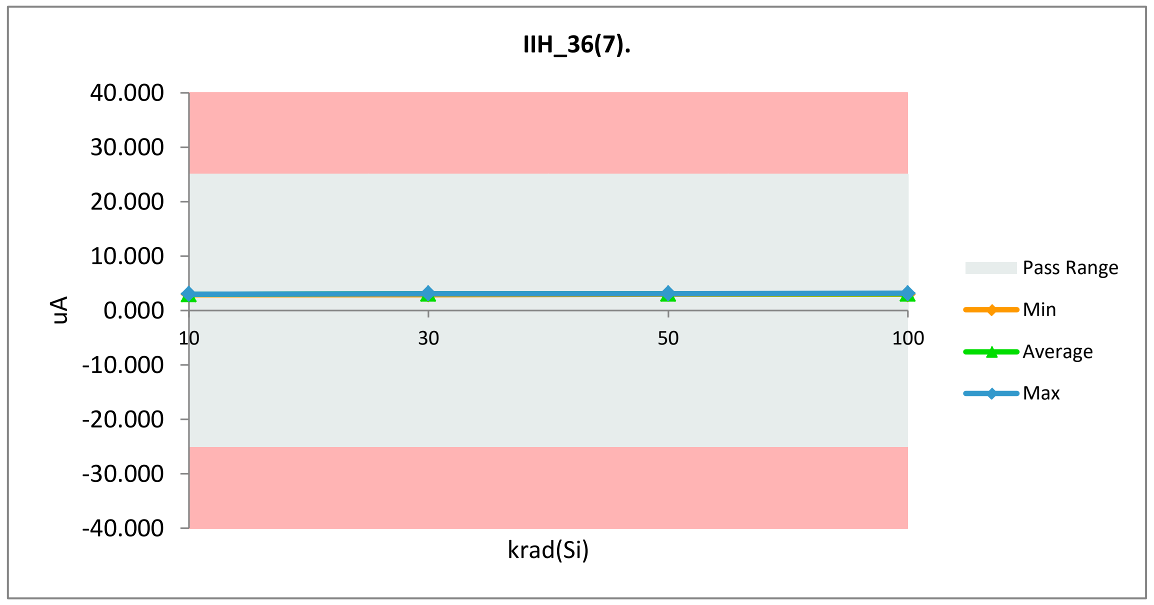


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(7).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	2.917	3.017	-0.100
10	7	2.973	2.942	0.031
10	8	2.898	3.017	-0.119
10	9	3.122	3.035	0.087
10	10	2.973	3.054	-0.081
30	6	3.069	3.148	-0.079
30	7	3.088	3.148	-0.060
30	8	3.013	2.944	0.069
30	9	3.032	3.074	-0.042
30	10	3.032	3.093	-0.061
50	16	3.051	3.130	-0.079
50	17	2.995	3.018	-0.023
50	18	3.069	3.093	-0.024
50	19	2.976	3.074	-0.098
50	20	3.032	3.111	-0.079
100	B043	2.976	3.018	-0.042
100	B044	3.069	3.037	0.032
100	B045	2.958	3.055	-0.097
100	B046	3.032	3.037	-0.005
100	B047	2.976	3.111	-0.135
100	B048	3.013	3.037	-0.023
100	B049	3.069	3.074	-0.005
100	B050	2.995	3.093	-0.098
100	B051	3.088	3.037	0.051
100	B052	3.013	3.074	-0.060
100	B053	2.939	3.148	-0.209
100	B054	3.013	3.055	-0.042
100	B055	3.088	3.167	-0.079
100	B056	3.032	3.093	-0.061
100	B057	2.939	2.999	-0.060
100	B058	2.976	3.093	-0.117
100	B059	2.939	3.148	-0.209
100	B060	2.976	3.093	-0.117
100	B061	3.032	2.981	0.051
100	B062	3.013	3.058	-0.045
100	B063	2.976	3.018	-0.042
100	B064	2.920	3.055	-0.135
	Max	3.122	3.167	0.087
	Average	3.008	3.064	-0.057
	Min	2.898	2.942	-0.209
	Std Dev	0.054	0.055	0.068

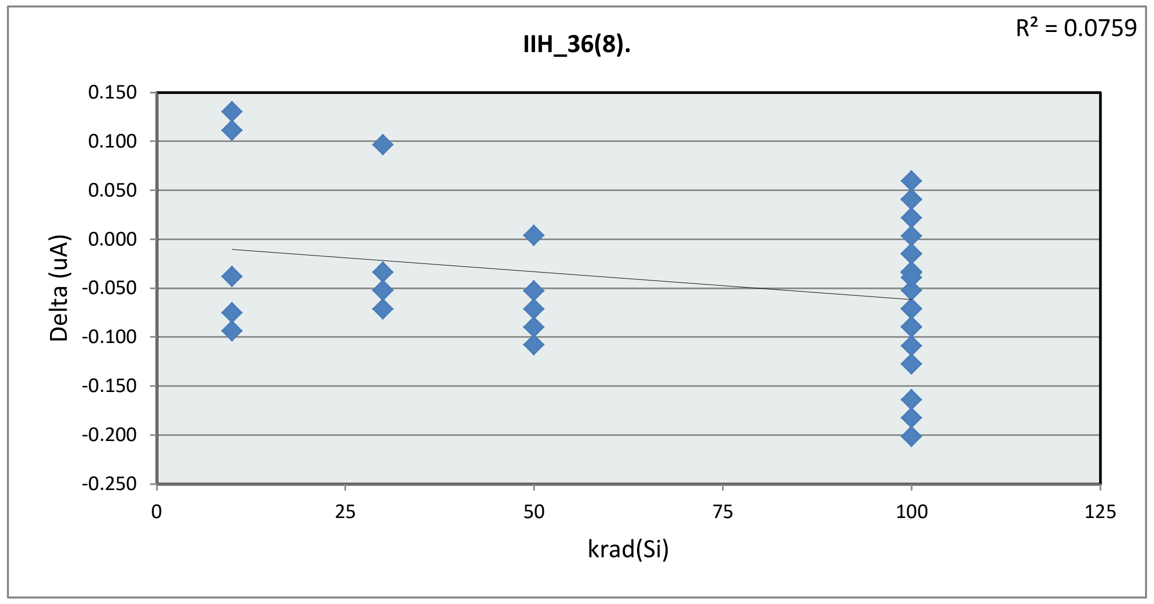


	IIH_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.942	2.944	3.018	2.981
Average	3.013	3.081	3.085	3.067
Max	3.054	3.148	3.130	3.167
UL	25.000	25.000	25.000	25.000

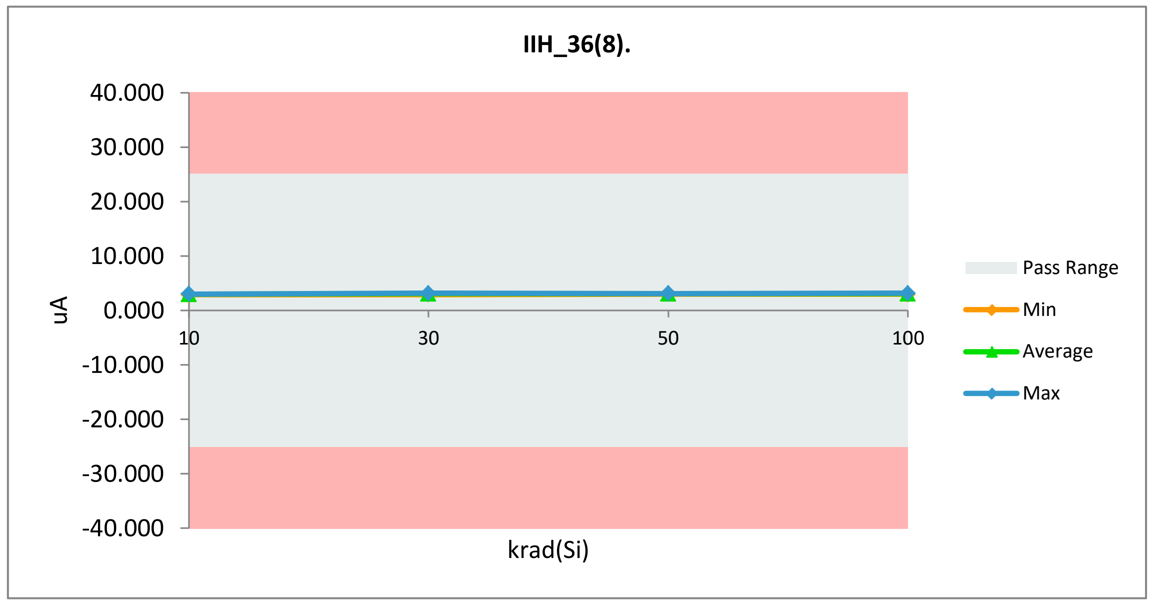


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(8).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	2.929	3.023	-0.094
10	7	2.985	2.874	0.111
10	8	2.911	2.986	-0.075
10	9	3.116	2.986	0.130
10	10	2.985	3.023	-0.038
30	6	3.074	3.145	-0.071
30	7	3.111	3.163	-0.052
30	8	3.036	2.940	0.096
30	9	3.036	3.070	-0.034
30	10	3.036	3.089	-0.053
50	16	3.055	3.145	-0.090
50	17	3.018	3.014	0.004
50	18	3.055	3.108	-0.053
50	19	2.962	3.070	-0.108
50	20	3.036	3.108	-0.072
100	B043	2.981	3.014	-0.033
100	B044	3.074	3.033	0.041
100	B045	2.981	3.052	-0.071
100	B046	3.018	3.052	-0.034
100	B047	2.962	3.126	-0.164
100	B048	3.018	3.033	-0.015
100	B049	3.074	3.052	0.022
100	B050	2.999	3.108	-0.109
100	B051	3.092	3.033	0.059
100	B052	3.036	3.070	-0.034
100	B053	2.943	3.126	-0.183
100	B054	3.055	3.052	0.003
100	B055	3.092	3.163	-0.071
100	B056	3.018	3.108	-0.090
100	B057	2.925	2.977	-0.052
100	B058	2.981	3.108	-0.127
100	B059	2.943	3.145	-0.202
100	B060	2.981	3.070	-0.089
100	B061	3.036	2.996	0.040
100	B062	3.018	3.057	-0.039
100	B063	2.999	3.014	-0.015
100	B064	2.925	3.052	-0.127
	Max	3.116	3.163	0.130
	Average	3.013	3.059	-0.046
	Min	2.911	2.874	-0.202
	Std Dev	0.054	0.064	0.075

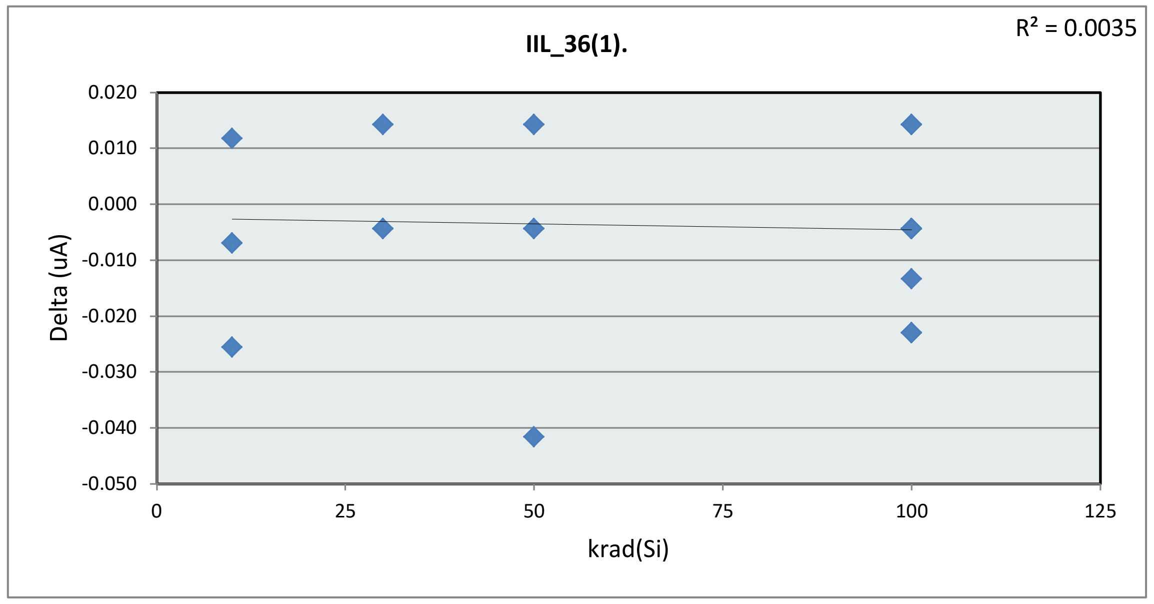


	IIH_36(8).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.874	2.940	3.014	2.977
Average	2.978	3.081	3.089	3.066
Max	3.023	3.163	3.145	3.163
UL	25.000	25.000	25.000	25.000

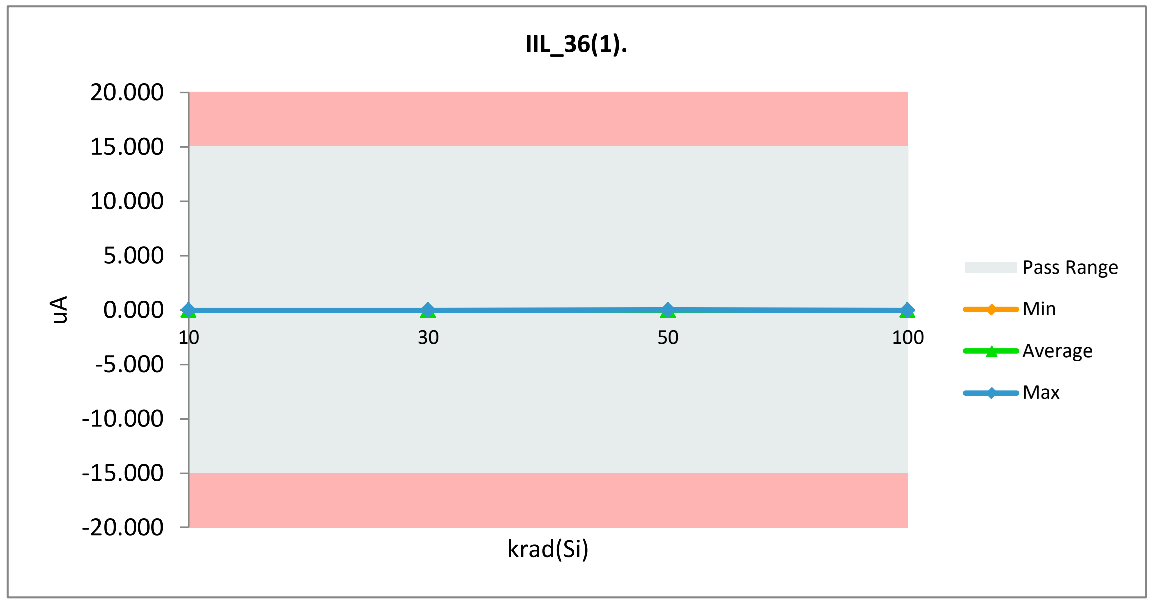


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIL_36(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.031	-0.024	-0.007
10	7	-0.031	-0.024	-0.007
10	8	-0.012	-0.024	0.012
10	9	-0.031	-0.024	-0.007
10	10	-0.049	-0.024	-0.026
30	6	-0.023	-0.037	0.014
30	7	-0.042	-0.037	-0.004
30	8	-0.023	-0.019	-0.004
30	9	-0.023	-0.019	-0.004
30	10	-0.023	-0.037	0.014
50	16	-0.023	-0.037	0.014
50	17	-0.042	0.000	-0.042
50	18	-0.042	-0.037	-0.004
50	19	-0.023	-0.019	-0.004
50	20	-0.023	-0.037	0.014
100	B043	-0.042	-0.037	-0.004
100	B044	-0.042	-0.019	-0.023
100	B045	-0.023	-0.019	-0.004
100	B046	-0.023	-0.019	-0.004
100	B047	-0.023	-0.037	0.014
100	B048	-0.023	-0.019	-0.004
100	B049	-0.023	-0.019	-0.004
100	B050	-0.042	-0.019	-0.023
100	B051	-0.042	-0.019	-0.023
100	B052	-0.042	-0.019	-0.023
100	B053	-0.023	-0.019	-0.004
100	B054	-0.023	-0.037	0.014
100	B055	-0.023	-0.019	-0.004
100	B056	-0.023	-0.019	-0.004
100	B057	-0.023	-0.019	-0.004
100	B058	-0.023	-0.019	-0.004
100	B059	-0.023	-0.019	-0.004
100	B060	-0.023	-0.037	0.014
100	B061	-0.023	-0.019	-0.004
100	B062	-0.042	-0.028	-0.013
100	B063	-0.023	-0.037	0.014
100	B064	-0.023	-0.019	-0.004
	Max	-0.012	0.000	0.014
	Average	-0.029	-0.025	-0.004
	Min	-0.049	-0.037	-0.042
	Std Dev	0.009	0.009	0.013

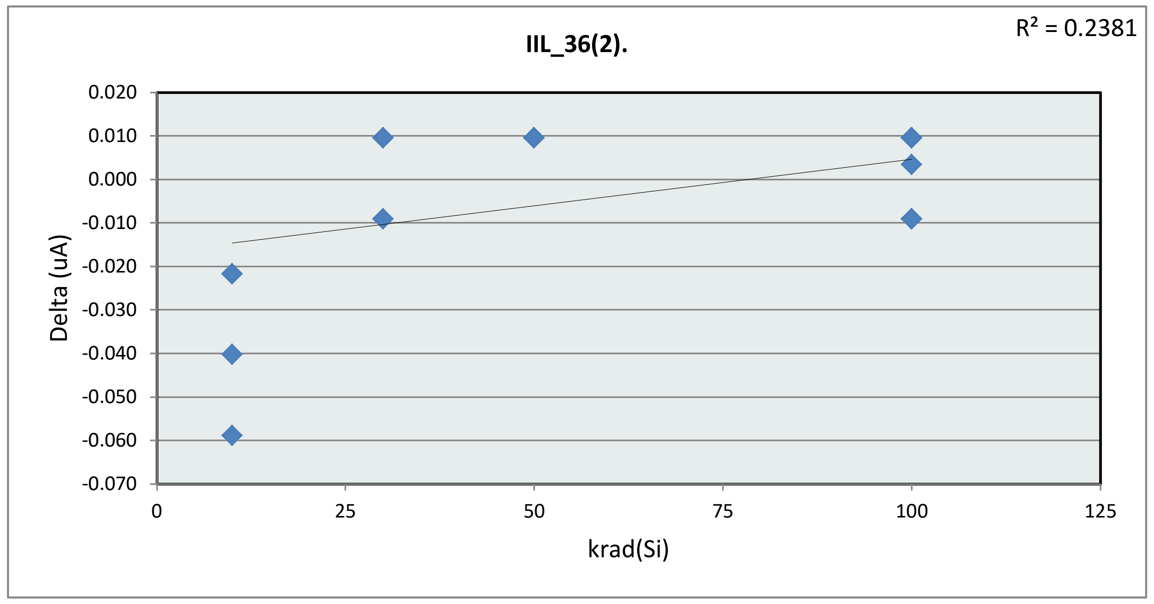


	IIL_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.024	-0.037	-0.037	-0.037
Average	-0.024	-0.030	-0.026	-0.023
Max	-0.024	-0.019	0.000	-0.019
UL	15.000	15.000	15.000	15.000

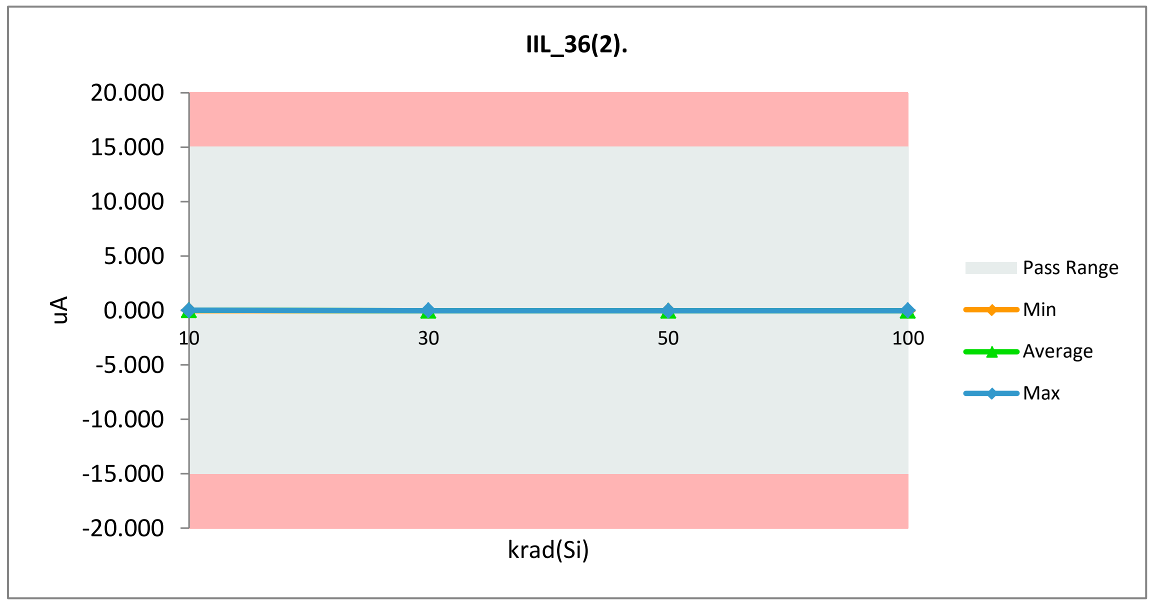


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIL_36(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.014	0.008	-0.022
10	7	-0.014	0.027	-0.040
10	8	-0.014	0.008	-0.022
10	9	-0.014	0.008	-0.022
10	10	-0.032	0.027	-0.059
30	6	-0.016	-0.025	0.009
30	7	-0.016	-0.025	0.009
30	8	-0.034	-0.025	-0.009
30	9	-0.016	-0.006	-0.009
30	10	-0.016	-0.025	0.009
50	16	-0.016	-0.025	0.009
50	17	-0.016	-0.025	0.009
50	18	-0.016	-0.025	0.009
50	19	-0.016	-0.025	0.009
50	20	-0.016	-0.025	0.009
100	B043	-0.034	-0.025	-0.009
100	B044	-0.016	-0.025	0.009
100	B045	-0.016	-0.025	0.009
100	B046	-0.034	-0.025	-0.009
100	B047	-0.016	-0.006	-0.009
100	B048	-0.016	-0.025	0.009
100	B049	-0.016	-0.025	0.009
100	B050	-0.016	-0.025	0.009
100	B051	-0.016	-0.025	0.009
100	B052	-0.034	-0.025	-0.009
100	B053	-0.016	-0.025	0.009
100	B054	-0.016	-0.025	0.009
100	B055	-0.034	-0.025	-0.009
100	B056	-0.034	-0.025	-0.009
100	B057	-0.034	-0.025	-0.009
100	B058	-0.016	-0.025	0.009
100	B059	-0.034	-0.025	-0.009
100	B060	-0.016	-0.025	0.009
100	B061	-0.016	-0.025	0.009
100	B062	-0.016	-0.019	0.003
100	B063	-0.016	-0.025	0.009
100	B064	-0.016	-0.025	0.009
	Max	-0.014	0.027	0.009
	Average	-0.020	-0.018	-0.001
	Min	-0.034	-0.025	-0.059
	Std Dev	0.008	0.015	0.016



	IIL_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	0.008	-0.025	-0.025	-0.025
Average	0.016	-0.021	-0.025	-0.024
Max	0.027	-0.006	-0.025	-0.006
UL	15.000	15.000	15.000	15.000



HDR UnBiased TID Report
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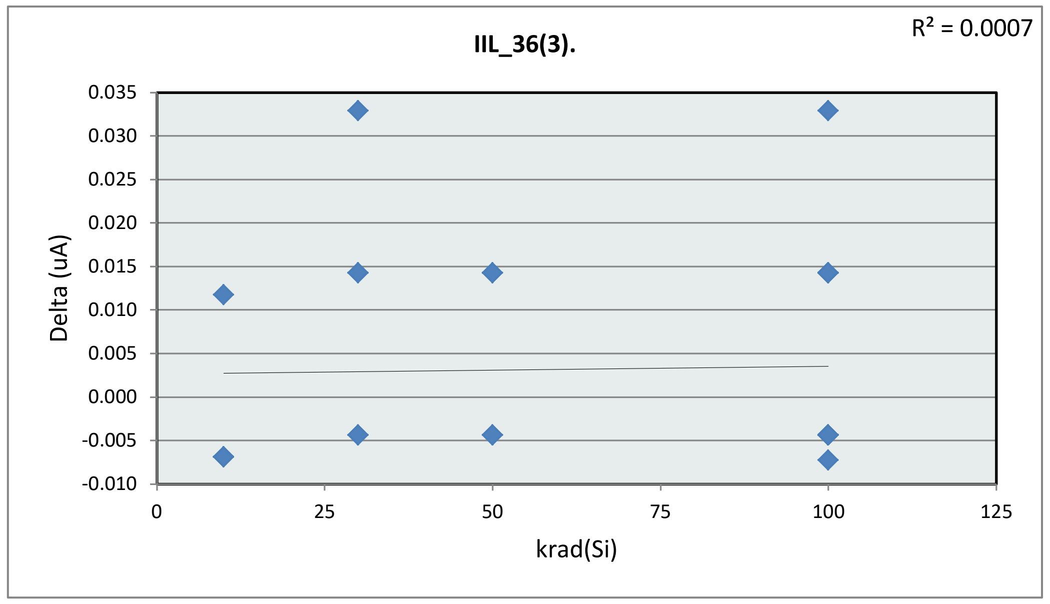
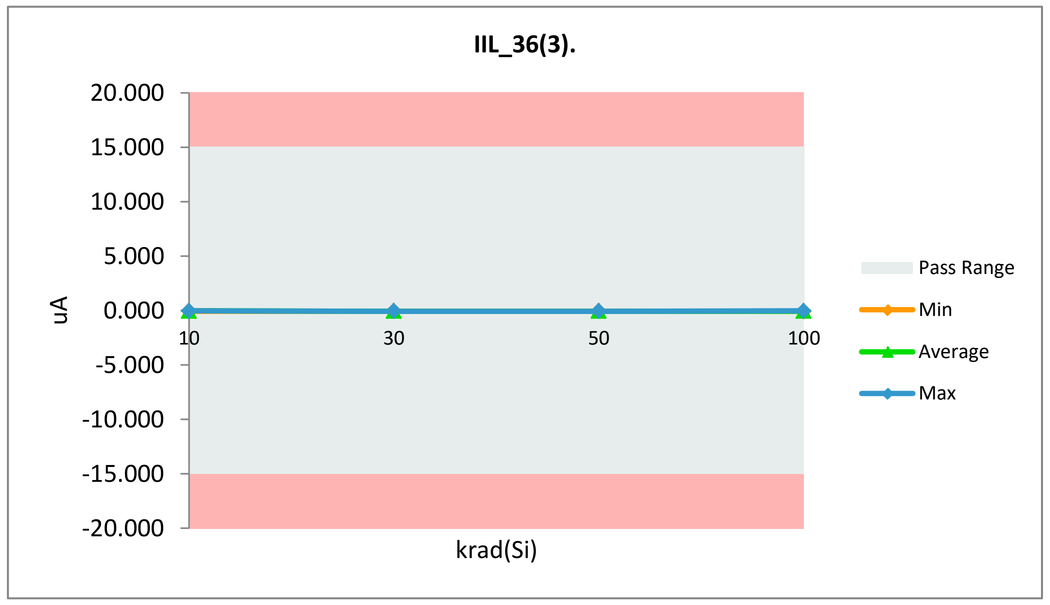
	IIL_36(3).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.025	-0.037	0.012
10	7	-0.025	-0.018	-0.007
10	8	-0.025	-0.018	-0.007
10	9	-0.025	-0.018	-0.007
10	10	-0.025	-0.018	-0.007
30	6	-0.023	-0.055	0.033
30	7	-0.041	-0.037	-0.004
30	8	-0.023	-0.037	0.014
30	9	-0.041	-0.037	-0.004
30	10	-0.023	-0.037	0.014
50	16	-0.041	-0.037	-0.004
50	17	-0.041	-0.037	-0.004
50	18	-0.041	-0.037	-0.004
50	19	-0.023	-0.037	0.014
50	20	-0.023	-0.037	0.014
100	B043	-0.023	-0.037	0.014
100	B044	-0.041	-0.037	-0.004
100	B045	-0.023	-0.018	-0.004
100	B046	-0.023	-0.037	0.014
100	B047	-0.023	-0.037	0.014
100	B048	-0.041	-0.037	-0.004
100	B049	-0.023	-0.018	-0.004
100	B050	-0.023	-0.037	0.014
100	B051	-0.041	-0.037	-0.004
100	B052	-0.041	-0.037	-0.004
100	B053	-0.023	-0.037	0.014
100	B054	-0.041	-0.037	-0.004
100	B055	-0.041	-0.037	-0.004
100	B056	-0.041	-0.074	0.033
100	B057	-0.023	-0.037	0.014
100	B058	-0.041	-0.037	-0.004
100	B059	-0.041	-0.037	-0.004
100	B060	-0.041	-0.037	-0.004
100	B061	-0.041	-0.037	-0.004
100	B062	-0.041	-0.034	-0.007
100	B063	-0.041	-0.037	-0.004
100	B064	-0.023	-0.037	0.014
	Max	-0.023	-0.018	0.033
	Average	-0.032	-0.035	0.003
	Min	-0.041	-0.074	-0.007
	Std Dev	0.009	0.010	0.011

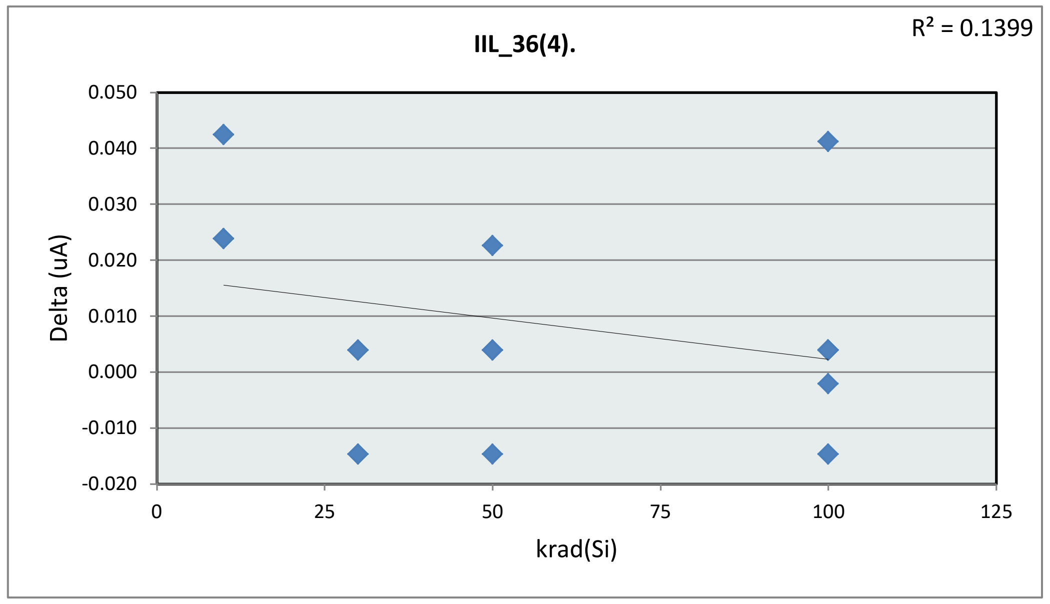


	IIL_36(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.037	-0.055	-0.037	-0.074
Average	-0.022	-0.040	-0.037	-0.037
Max	-0.018	-0.037	-0.037	-0.018
UL	15.000	15.000	15.000	15.000

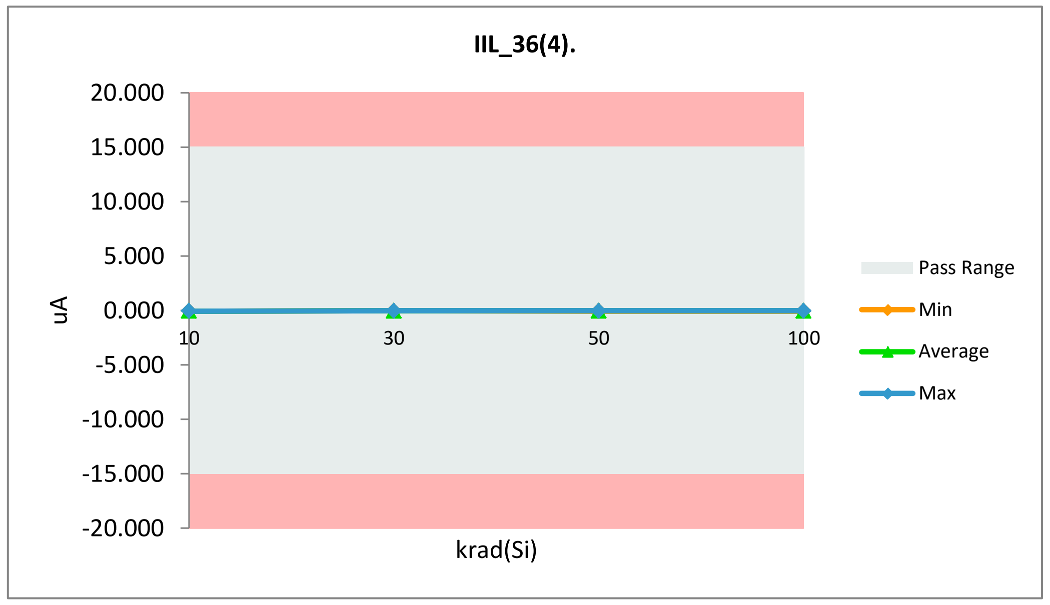


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIL_36(4).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.013	-0.036	0.024
10	7	-0.013	-0.036	0.024
10	8	-0.013	-0.055	0.042
10	9	-0.013	-0.055	0.042
10	10	-0.013	-0.036	0.024
30	6	-0.036	-0.021	-0.015
30	7	-0.036	-0.021	-0.015
30	8	-0.017	-0.021	0.004
30	9	-0.017	-0.021	0.004
30	10	-0.017	-0.021	0.004
50	16	-0.036	-0.021	-0.015
50	17	-0.017	-0.021	0.004
50	18	-0.017	-0.040	0.023
50	19	-0.017	-0.021	0.004
50	20	-0.017	-0.021	0.004
100	B043	-0.017	-0.059	0.041
100	B044	-0.017	-0.021	0.004
100	B045	-0.036	-0.021	-0.015
100	B046	-0.017	-0.021	0.004
100	B047	-0.017	-0.021	0.004
100	B048	-0.017	-0.021	0.004
100	B049	-0.017	-0.021	0.004
100	B050	-0.017	-0.021	0.004
100	B051	-0.017	-0.021	0.004
100	B052	-0.017	-0.021	0.004
100	B053	-0.017	-0.021	0.004
100	B054	-0.017	-0.021	0.004
100	B055	-0.017	-0.021	0.004
100	B056	-0.017	-0.021	0.004
100	B057	-0.017	-0.021	0.004
100	B058	-0.017	-0.021	0.004
100	B059	-0.017	-0.021	0.004
100	B060	-0.017	-0.021	0.004
100	B061	-0.036	-0.021	-0.015
100	B062	-0.017	-0.015	-0.002
100	B063	-0.017	-0.021	0.004
100	B064	-0.017	-0.021	0.004
	Max	-0.013	-0.015	0.042
	Average	-0.019	-0.026	0.006
	Min	-0.036	-0.059	-0.015
	Std Dev	0.007	0.011	0.014



	IIL_36(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.055	-0.021	-0.040	-0.059
Average	-0.044	-0.021	-0.025	-0.023
Max	-0.036	-0.021	-0.021	-0.015
UL	15.000	15.000	15.000	15.000



HDR UnBiased TID Report
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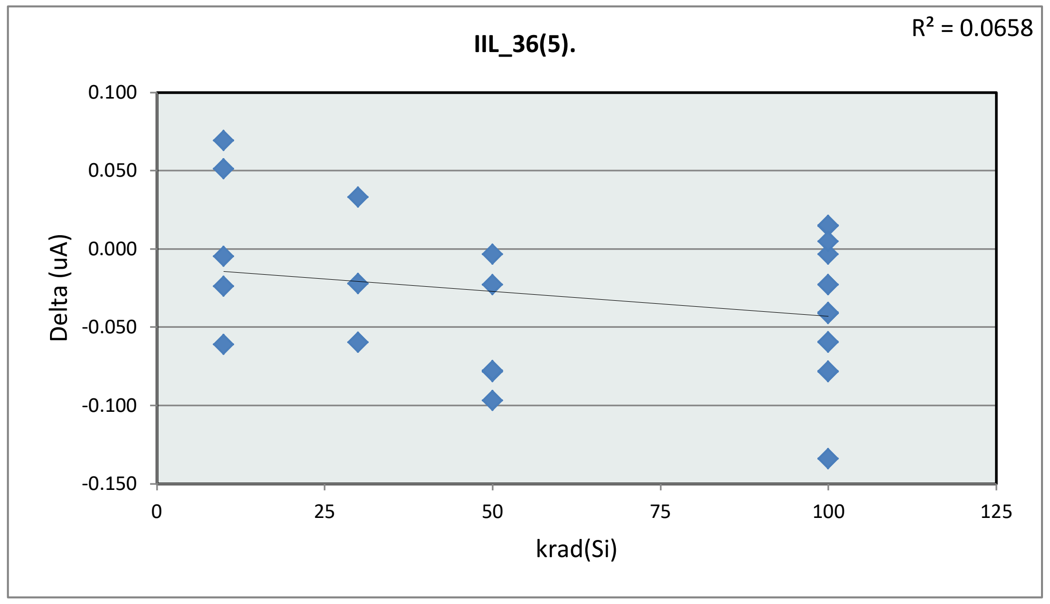
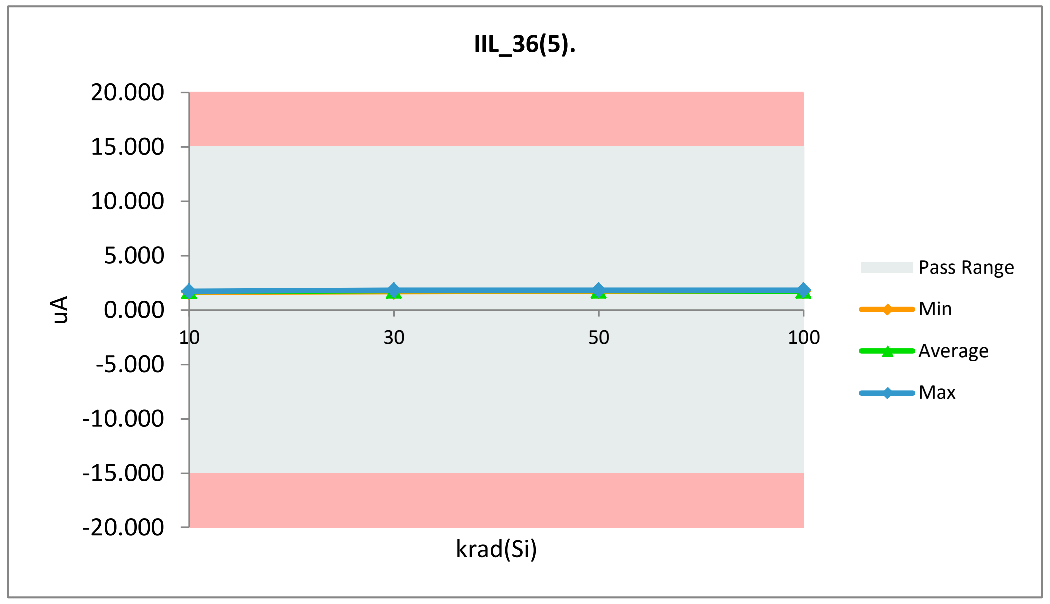
	IIL_36(5).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.646	1.707	-0.061
10	7	1.702	1.633	0.069
10	8	1.664	1.688	-0.024
10	9	1.758	1.707	0.051
10	10	1.702	1.707	-0.005
30	6	1.746	1.806	-0.060
30	7	1.746	1.806	-0.060
30	8	1.709	1.676	0.033
30	9	1.728	1.750	-0.022
30	10	1.728	1.750	-0.022
50	16	1.709	1.806	-0.097
50	17	1.709	1.732	-0.023
50	18	1.746	1.750	-0.004
50	19	1.691	1.769	-0.078
50	20	1.709	1.787	-0.078
100	B043	1.691	1.732	-0.041
100	B044	1.746	1.732	0.014
100	B045	1.691	1.732	-0.041
100	B046	1.746	1.750	-0.004
100	B047	1.691	1.769	-0.078
100	B048	1.709	1.732	-0.023
100	B049	1.765	1.750	0.015
100	B050	1.709	1.769	-0.060
100	B051	1.746	1.732	0.014
100	B052	1.728	1.769	-0.041
100	B053	1.672	1.806	-0.134
100	B054	1.709	1.732	-0.023
100	B055	1.746	1.787	-0.041
100	B056	1.709	1.750	-0.041
100	B057	1.672	1.713	-0.041
100	B058	1.691	1.769	-0.078
100	B059	1.672	1.806	-0.134
100	B060	1.691	1.750	-0.059
100	B061	1.728	1.713	0.015
100	B062	1.728	1.723	0.005
100	B063	1.709	1.732	-0.023
100	B064	1.672	1.750	-0.078
	Max	1.765	1.806	0.069
	Average	1.711	1.745	-0.034
	Min	1.646	1.633	-0.134
	Std Dev	0.029	0.039	0.045



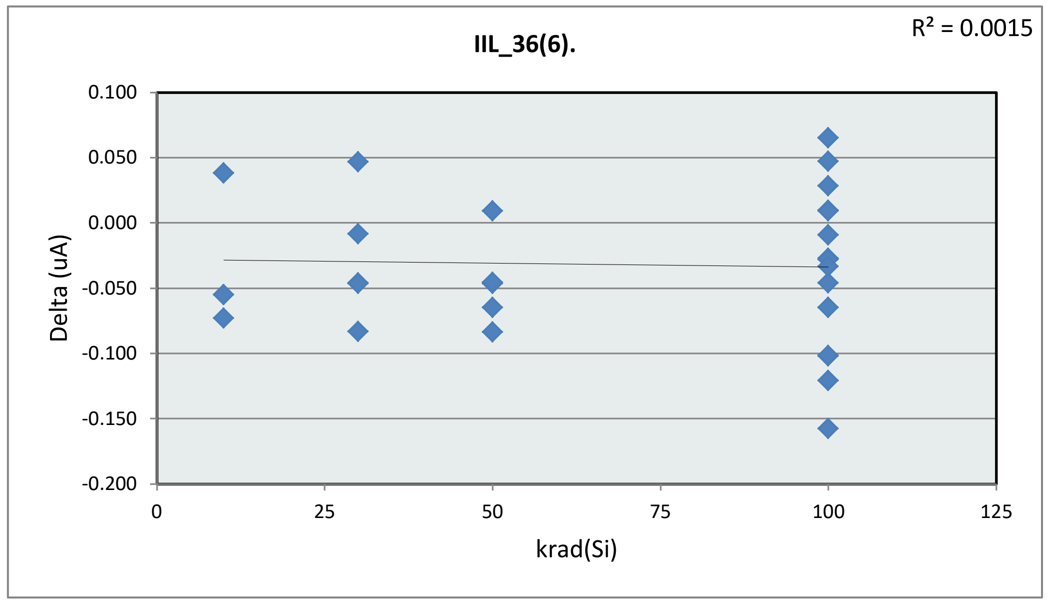
	IIL_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.633	1.676	1.732	1.713
Average	1.688	1.758	1.769	1.750
Max	1.707	1.806	1.806	1.806
UL	15.000	15.000	15.000	15.000



HDR UnBiased TID Report
SN55LVCP22A-SP

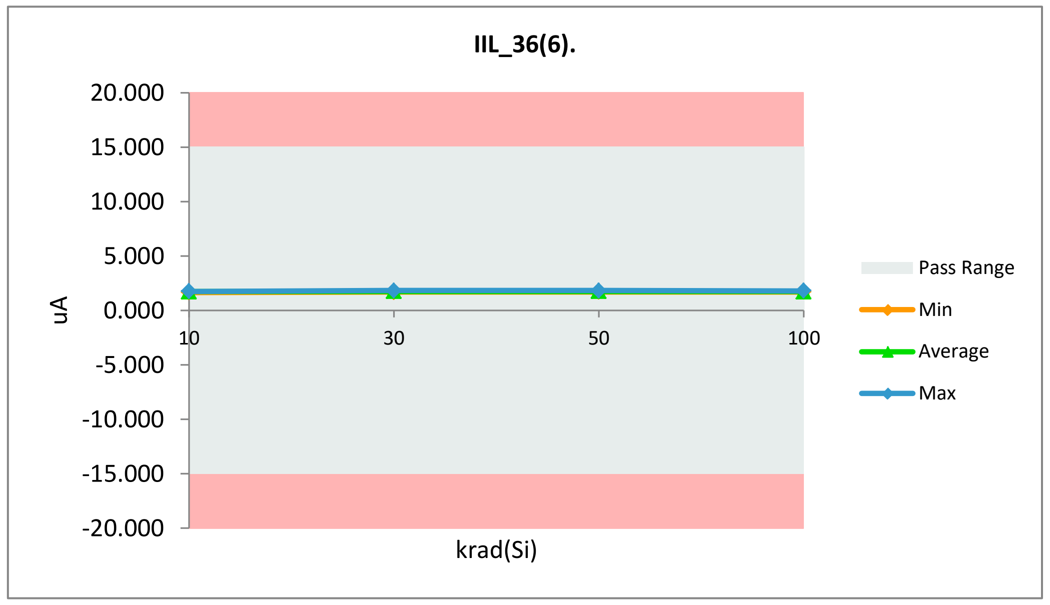
	IIL_36(6).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.678	1.751	-0.073
10	7	1.715	1.677	0.038
10	8	1.678	1.733	-0.055
10	9	1.789	1.751	0.038
10	10	1.715	1.770	-0.055
30	6	1.769	1.815	-0.046
30	7	1.788	1.834	-0.046
30	8	1.732	1.685	0.047
30	9	1.750	1.759	-0.009
30	10	1.695	1.778	-0.083
50	16	1.750	1.834	-0.084
50	17	1.713	1.704	0.009
50	18	1.713	1.778	-0.065
50	19	1.695	1.741	-0.046
50	20	1.713	1.759	-0.046
100	B043	1.695	1.704	-0.009
100	B044	1.769	1.704	0.065
100	B045	1.676	1.741	-0.065
100	B046	1.750	1.741	0.009
100	B047	1.676	1.797	-0.121
100	B048	1.695	1.722	-0.027
100	B049	1.769	1.722	0.047
100	B050	1.676	1.778	-0.102
100	B051	1.769	1.704	0.065
100	B052	1.750	1.741	0.009
100	B053	1.676	1.797	-0.121
100	B054	1.750	1.722	0.028
100	B055	1.788	1.815	-0.027
100	B056	1.750	1.778	-0.028
100	B057	1.676	1.704	-0.028
100	B058	1.732	1.778	-0.046
100	B059	1.657	1.815	-0.158
100	B060	1.713	1.778	-0.065
100	B061	1.695	1.704	-0.009
100	B062	1.732	1.765	-0.033
100	B063	1.713	1.704	0.009
100	B064	1.657	1.759	-0.102
	Max	1.789	1.834	0.065
	Average	1.720	1.752	-0.032
	Min	1.657	1.677	-0.158
	Std Dev	0.039	0.042	0.054



	IIL_36(6).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	15	uA
Min Limit	-15	uA

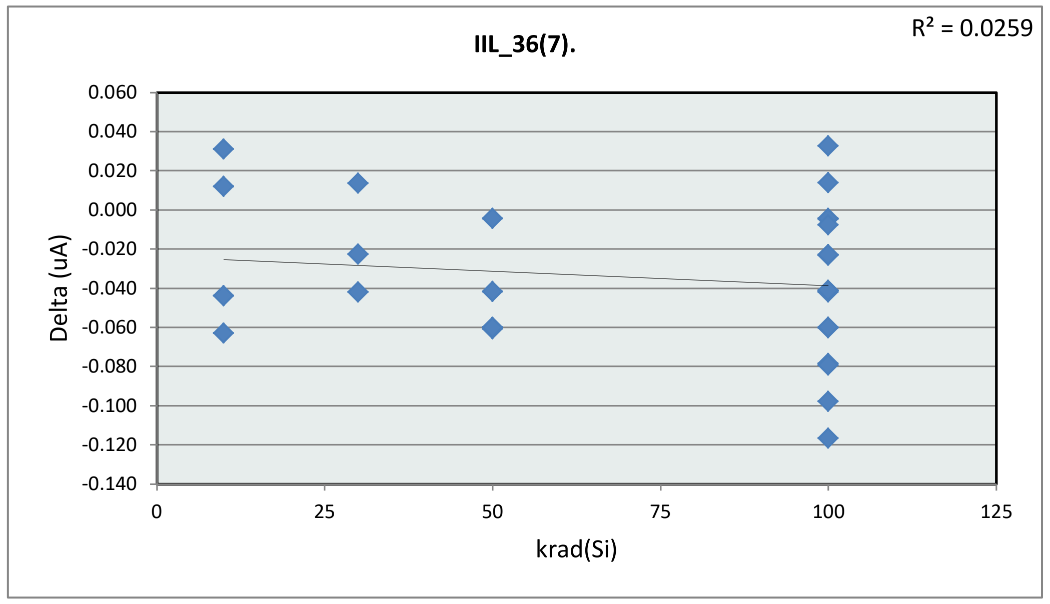
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.677	1.685	1.704	1.704
Average	1.736	1.774	1.763	1.749
Max	1.770	1.834	1.834	1.815
UL	15.000	15.000	15.000	15.000



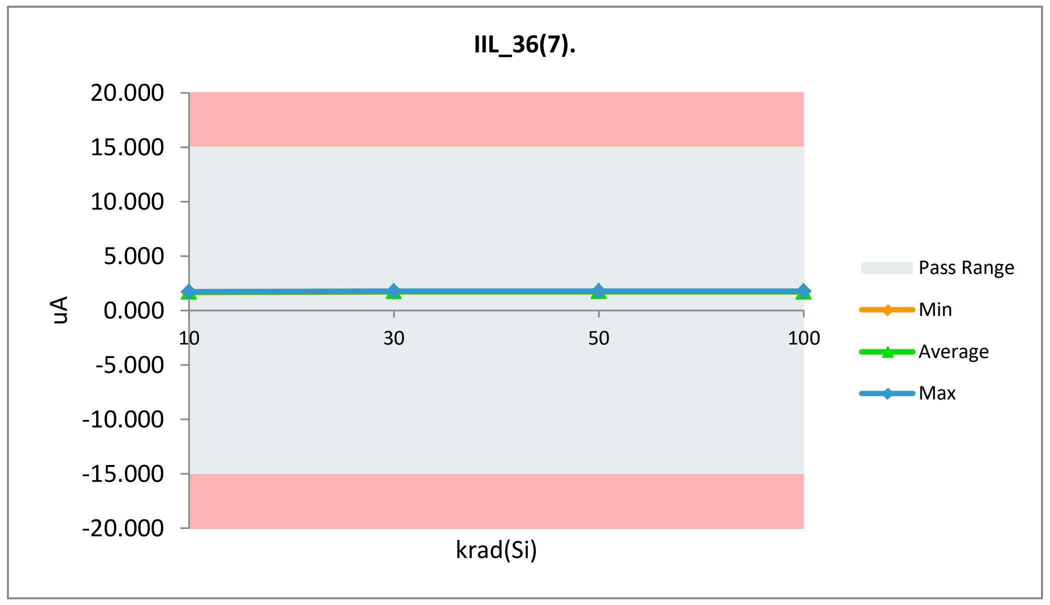
HDR UnBiased TID Report
SN55LVCP22A-SP

	IIL_36(7).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.669	1.713	-0.044
10	7	1.688	1.676	0.012
10	8	1.669	1.713	-0.044
10	9	1.763	1.732	0.031
10	10	1.688	1.751	-0.063
30	6	1.747	1.789	-0.042
30	7	1.747	1.789	-0.042
30	8	1.710	1.696	0.014
30	9	1.728	1.751	-0.023
30	10	1.728	1.751	-0.023
50	16	1.728	1.789	-0.061
50	17	1.710	1.714	-0.004
50	18	1.728	1.770	-0.042
50	19	1.691	1.751	-0.060
50	20	1.710	1.770	-0.060
100	B043	1.691	1.714	-0.023
100	B044	1.728	1.733	-0.005
100	B045	1.672	1.751	-0.079
100	B046	1.728	1.733	-0.005
100	B047	1.710	1.770	-0.060
100	B048	1.710	1.733	-0.023
100	B049	1.747	1.733	0.014
100	B050	1.710	1.770	-0.060
100	B051	1.766	1.733	0.033
100	B052	1.710	1.751	-0.041
100	B053	1.672	1.789	-0.117
100	B054	1.710	1.733	-0.023
100	B055	1.747	1.789	-0.042
100	B056	1.710	1.751	-0.041
100	B057	1.672	1.714	-0.042
100	B058	1.710	1.751	-0.041
100	B059	1.691	1.789	-0.098
100	B060	1.691	1.751	-0.060
100	B061	1.710	1.714	-0.004
100	B062	1.728	1.736	-0.008
100	B063	1.691	1.714	-0.023
100	B064	1.654	1.733	-0.079
	Max	1.766	1.789	0.033
	Average	1.710	1.744	-0.035
	Min	1.654	1.676	-0.117
	Std Dev	0.027	0.029	0.034

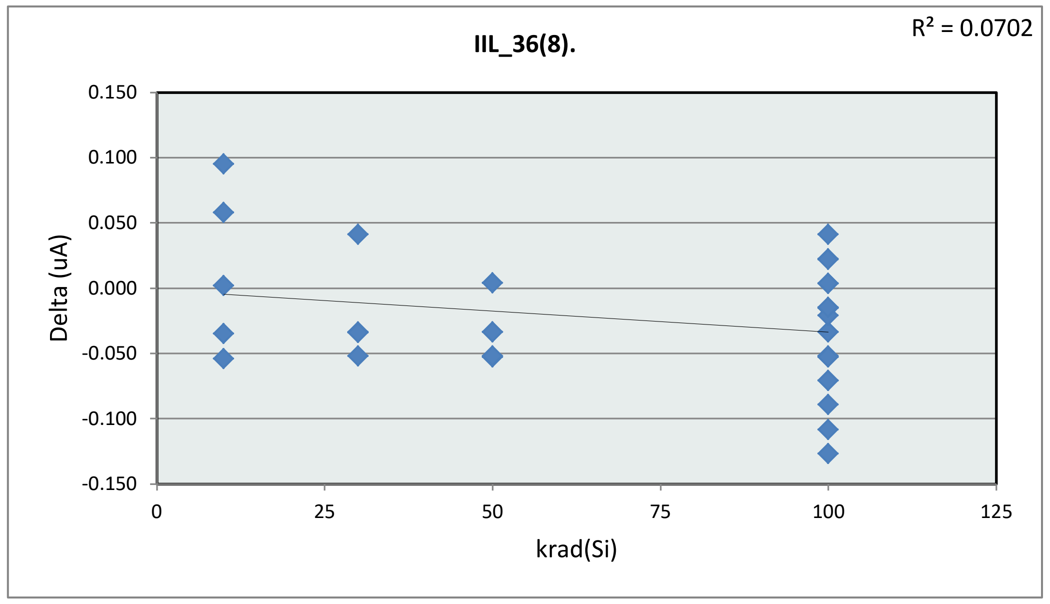


	IIL_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.676	1.696	1.714	1.714
Average	1.717	1.755	1.759	1.745
Max	1.751	1.789	1.789	1.789
UL	15.000	15.000	15.000	15.000

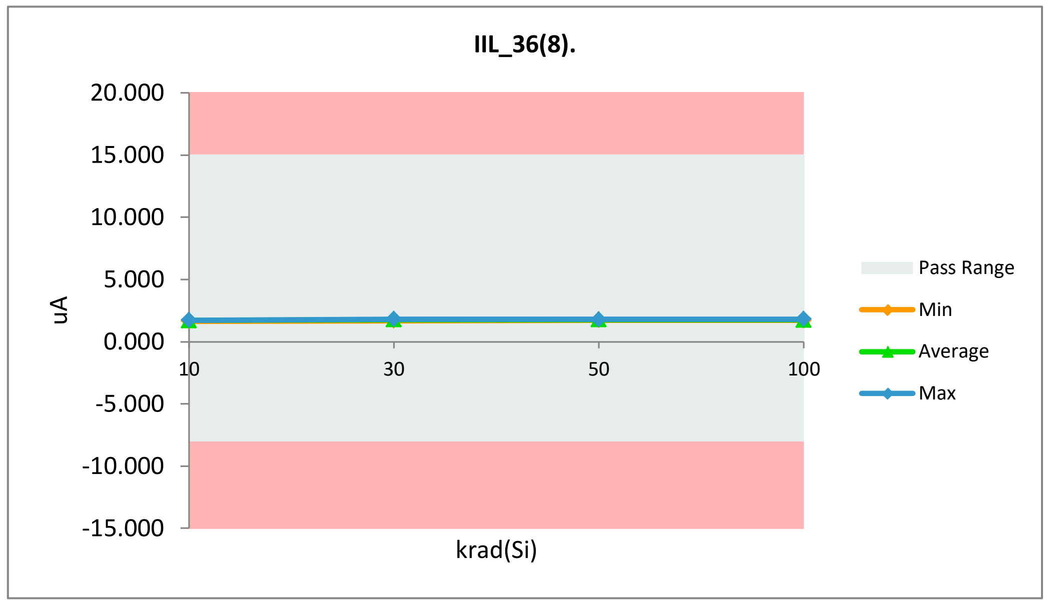


HDR UnBiased TID Report
SN55LVCP22A-SP

		IIL_36(8).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.682	1.736	-0.054
10	7	1.700	1.642	0.058
10	8	1.663	1.698	-0.035
10	9	1.793	1.698	0.095
10	10	1.719	1.717	0.002
30	6	1.770	1.804	-0.034
30	7	1.770	1.822	-0.052
30	8	1.733	1.692	0.041
30	9	1.733	1.767	-0.034
30	10	1.733	1.767	-0.034
50	16	1.752	1.785	-0.033
50	17	1.733	1.729	0.004
50	18	1.752	1.785	-0.033
50	19	1.714	1.767	-0.053
50	20	1.733	1.785	-0.052
100	B043	1.714	1.729	-0.015
100	B044	1.752	1.748	0.004
100	B045	1.714	1.748	-0.034
100	B046	1.752	1.748	0.004
100	B047	1.696	1.785	-0.089
100	B048	1.733	1.748	-0.015
100	B049	1.770	1.748	0.022
100	B050	1.714	1.785	-0.071
100	B051	1.770	1.729	0.041
100	B052	1.752	1.767	-0.015
100	B053	1.677	1.804	-0.127
100	B054	1.752	1.748	0.004
100	B055	1.770	1.804	-0.034
100	B056	1.733	1.785	-0.052
100	B057	1.696	1.711	-0.015
100	B058	1.714	1.767	-0.053
100	B059	1.696	1.804	-0.108
100	B060	1.714	1.767	-0.053
100	B061	1.733	1.711	0.022
100	B062	1.733	1.754	-0.021
100	B063	1.714	1.729	-0.015
100	B064	1.677	1.748	-0.071
	Max	1.793	1.822	0.095
	Average	1.729	1.753	-0.024
	Min	1.663	1.642	-0.127
	Std Dev	0.030	0.038	0.044



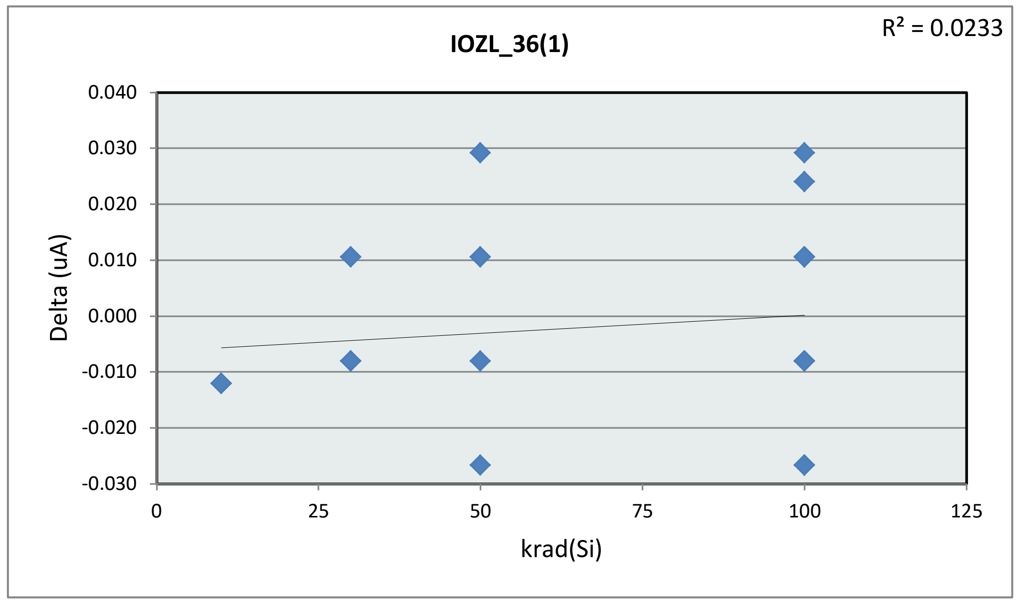
	IIL_36(8).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-8	uA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	1.642	1.692	1.729	1.711
Average	1.698	1.770	1.770	1.758
Max	1.736	1.822	1.785	1.804
UL	15.000	15.000	15.000	15.000



HDR UnBiased TID Report
SN55LVCP22A-SP

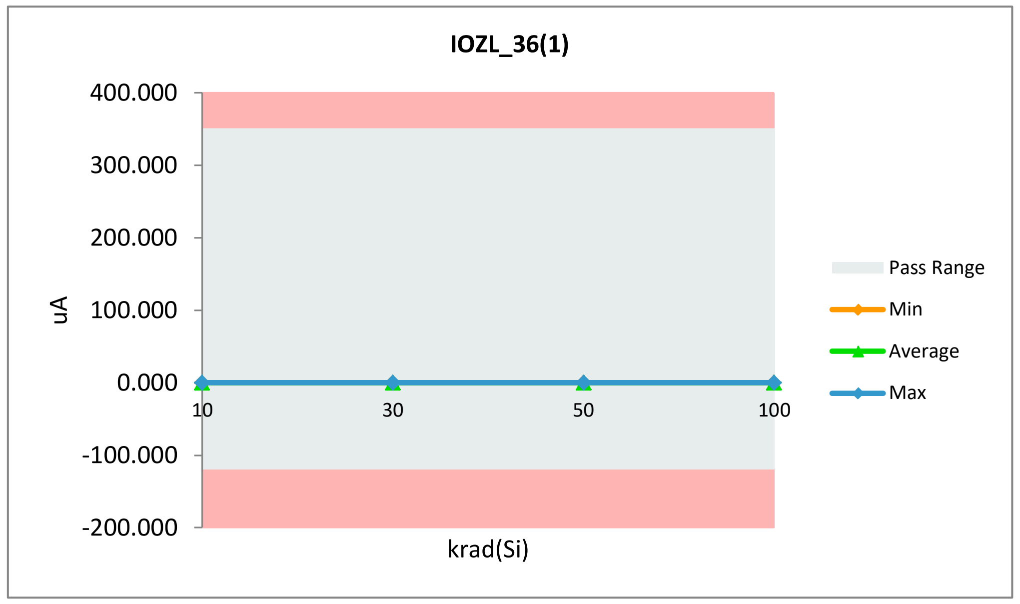
	IOZL_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.028	-0.016	-0.012
10	7	-0.028	-0.016	-0.012
10	8	-0.028	-0.016	-0.012
10	9	-0.028	-0.016	-0.012
10	10	-0.028	-0.016	-0.012
30	6	0.003	0.011	-0.008
30	7	0.003	0.011	-0.008
30	8	0.003	-0.007	0.011
30	9	0.003	-0.007	0.011
30	10	0.003	0.011	-0.008
50	16	0.022	0.011	0.011
50	17	-0.015	0.011	-0.027
50	18	-0.015	-0.007	-0.008
50	19	0.022	-0.007	0.029
50	20	0.022	0.011	0.011
100	B043	0.003	-0.007	0.011
100	B044	0.003	0.011	-0.008
100	B045	0.003	-0.007	0.011
100	B046	-0.015	0.011	-0.027
100	B047	0.003	-0.007	0.011
100	B048	-0.015	0.011	-0.027
100	B049	-0.015	-0.007	-0.008
100	B050	-0.015	-0.007	-0.008
100	B051	-0.015	0.011	-0.027
100	B052	-0.015	-0.007	-0.008
100	B053	0.022	-0.007	0.029
100	B054	0.003	-0.007	0.011
100	B055	-0.015	0.011	-0.027
100	B056	-0.015	-0.007	-0.008
100	B057	0.003	0.011	-0.008
100	B058	0.003	-0.007	0.011
100	B059	0.003	-0.007	0.011
100	B060	0.003	-0.007	0.011
100	B061	0.003	-0.007	0.011
100	B062	0.003	-0.021	0.024
100	B063	0.003	-0.007	0.011
100	B064	0.003	0.011	-0.008
	Max	0.022	0.011	0.029
	Average	-0.004	-0.002	-0.002
	Min	-0.028	-0.021	-0.027
	Std Dev	0.015	0.011	0.015



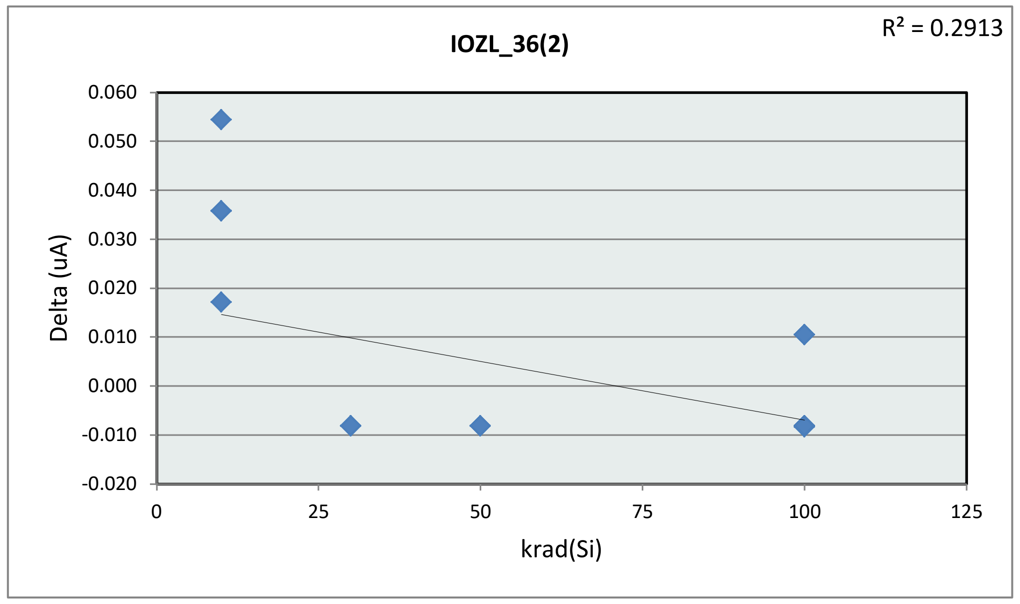
	IOZL_36(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	350	uA
Min Limit	-120	uA

krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.016	-0.007	-0.007	-0.021
Average	-0.016	0.004	0.004	-0.002
Max	-0.016	0.011	0.011	0.011
UL	350.000	350.000	350.000	350.000

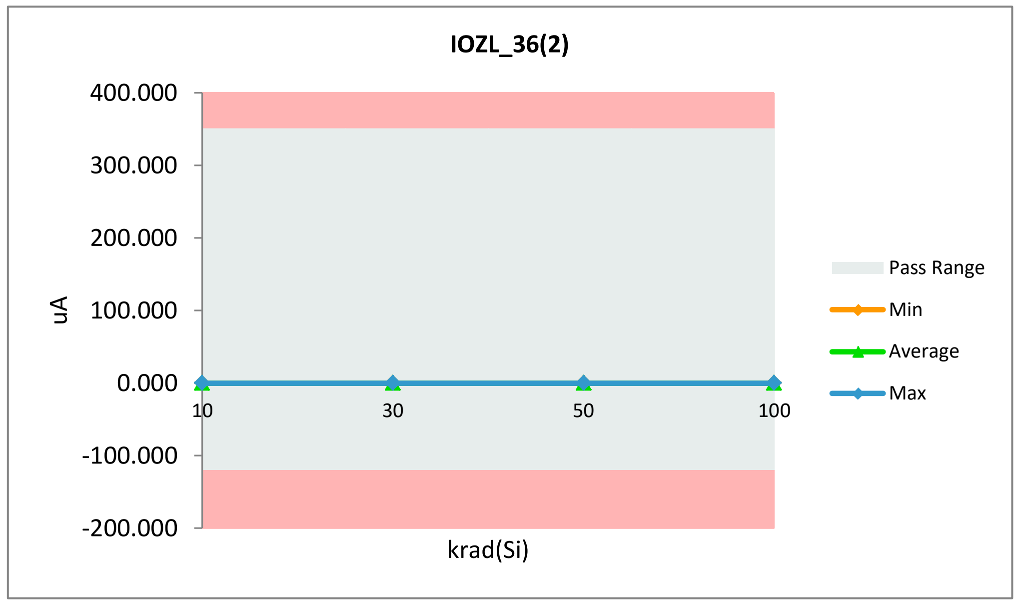


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOZL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.008	-0.046	0.054
10	7	0.008	-0.027	0.036
10	8	-0.010	-0.046	0.036
10	9	-0.010	-0.027	0.017
10	10	-0.010	-0.046	0.036
30	6	-0.005	0.003	-0.008
30	7	-0.005	0.003	-0.008
30	8	-0.005	0.003	-0.008
30	9	-0.005	0.003	-0.008
30	10	-0.005	0.003	-0.008
50	16	-0.005	0.003	-0.008
50	17	-0.005	0.003	-0.008
50	18	-0.005	0.003	-0.008
50	19	-0.005	0.003	-0.008
50	20	-0.005	0.003	-0.008
100	B043	0.013	0.003	0.011
100	B044	-0.005	0.003	-0.008
100	B045	-0.005	0.003	-0.008
100	B046	-0.005	0.003	-0.008
100	B047	-0.005	0.003	-0.008
100	B048	-0.005	0.003	-0.008
100	B049	-0.005	0.003	-0.008
100	B050	-0.005	0.003	-0.008
100	B051	-0.005	0.003	-0.008
100	B052	-0.005	0.003	-0.008
100	B053	-0.005	0.003	-0.008
100	B054	-0.005	0.003	-0.008
100	B055	-0.005	0.003	-0.008
100	B056	0.013	0.003	0.011
100	B057	-0.005	0.003	-0.008
100	B058	-0.005	0.003	-0.008
100	B059	-0.005	0.003	-0.008
100	B060	0.013	0.003	0.011
100	B061	0.013	0.003	0.011
100	B062	-0.005	0.003	-0.008
100	B063	-0.005	0.003	-0.008
100	B064	-0.005	0.003	-0.008
	Max	0.013	0.003	0.054
	Average	-0.003	-0.003	0.000
	Min	-0.010	-0.046	-0.008
	Std Dev	0.007	0.015	0.016

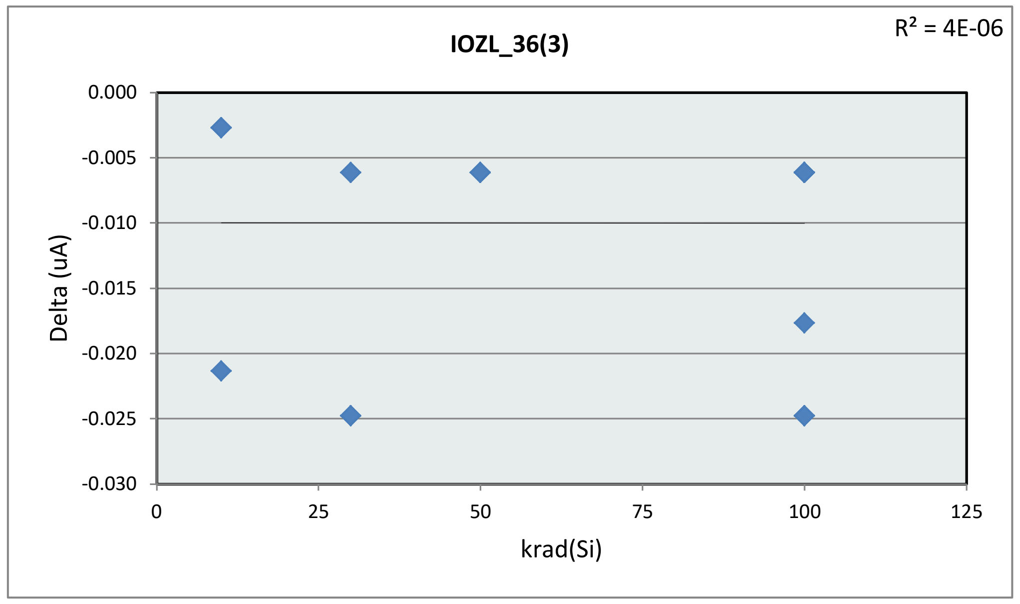


	IOZL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.046	0.003	0.003	0.003
Average	-0.039	0.003	0.003	0.003
Max	-0.027	0.003	0.003	0.003
UL	350.000	350.000	350.000	350.000

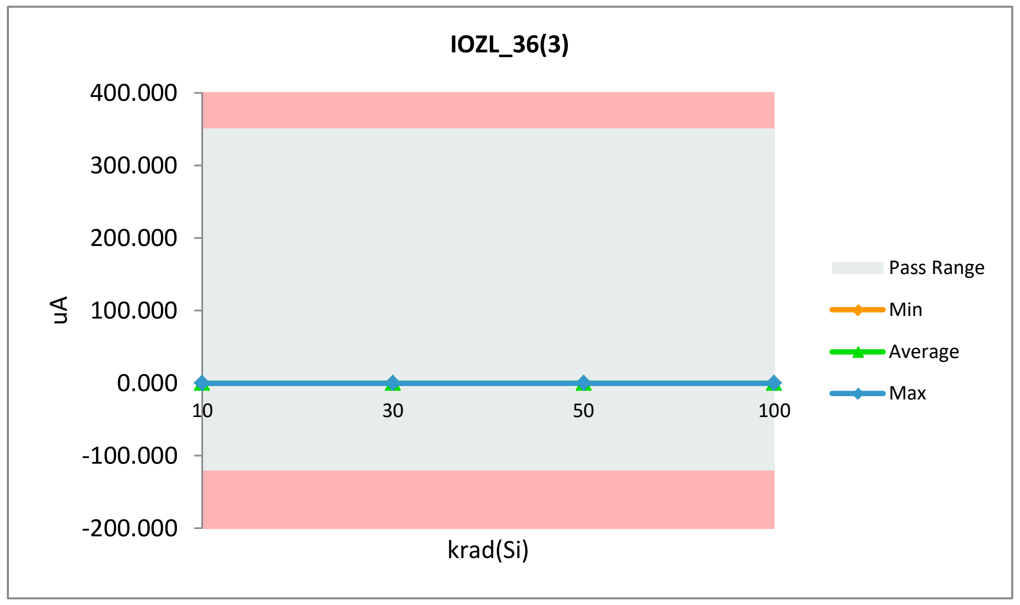


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOZL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.002	0.001	-0.003
10	7	-0.002	0.019	-0.021
10	8	-0.002	0.001	-0.003
10	9	-0.002	0.001	-0.003
10	10	-0.002	0.001	-0.003
30	6	-0.016	0.009	-0.025
30	7	-0.035	-0.010	-0.025
30	8	-0.016	-0.010	-0.006
30	9	-0.016	0.009	-0.025
30	10	-0.016	-0.010	-0.006
50	16	-0.016	-0.010	-0.006
50	17	-0.016	-0.010	-0.006
50	18	-0.016	-0.010	-0.006
50	19	-0.016	-0.010	-0.006
50	20	-0.016	-0.010	-0.006
100	B043	-0.016	-0.010	-0.006
100	B044	-0.016	-0.010	-0.006
100	B045	-0.016	0.009	-0.025
100	B046	-0.016	-0.010	-0.006
100	B047	-0.016	-0.010	-0.006
100	B048	-0.016	-0.010	-0.006
100	B049	-0.016	-0.010	-0.006
100	B050	-0.035	-0.010	-0.025
100	B051	-0.016	0.009	-0.025
100	B052	-0.016	-0.010	-0.006
100	B053	-0.016	-0.010	-0.006
100	B054	-0.016	-0.010	-0.006
100	B055	-0.016	-0.010	-0.006
100	B056	-0.016	-0.010	-0.006
100	B057	-0.016	-0.010	-0.006
100	B058	-0.016	-0.010	-0.006
100	B059	-0.016	-0.010	-0.006
100	B060	-0.016	-0.010	-0.006
100	B061	-0.016	0.009	-0.025
100	B062	-0.016	0.002	-0.018
100	B063	-0.016	-0.010	-0.006
100	B064	-0.016	-0.010	-0.006
	Max	-0.002	0.019	-0.003
	Average	-0.015	-0.005	-0.010
	Min	-0.035	-0.010	-0.025
	Std Dev	0.007	0.008	0.008

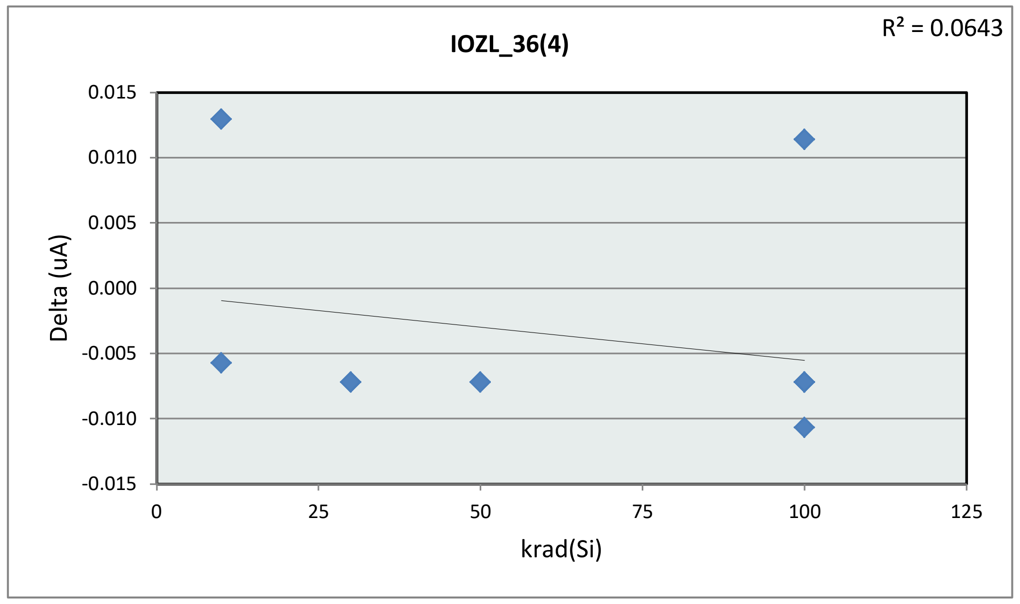


	IOZL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.001	-0.010	-0.010	-0.010
Average	0.005	-0.002	-0.010	-0.007
Max	0.019	0.009	-0.010	0.009
UL	350.000	350.000	350.000	350.000

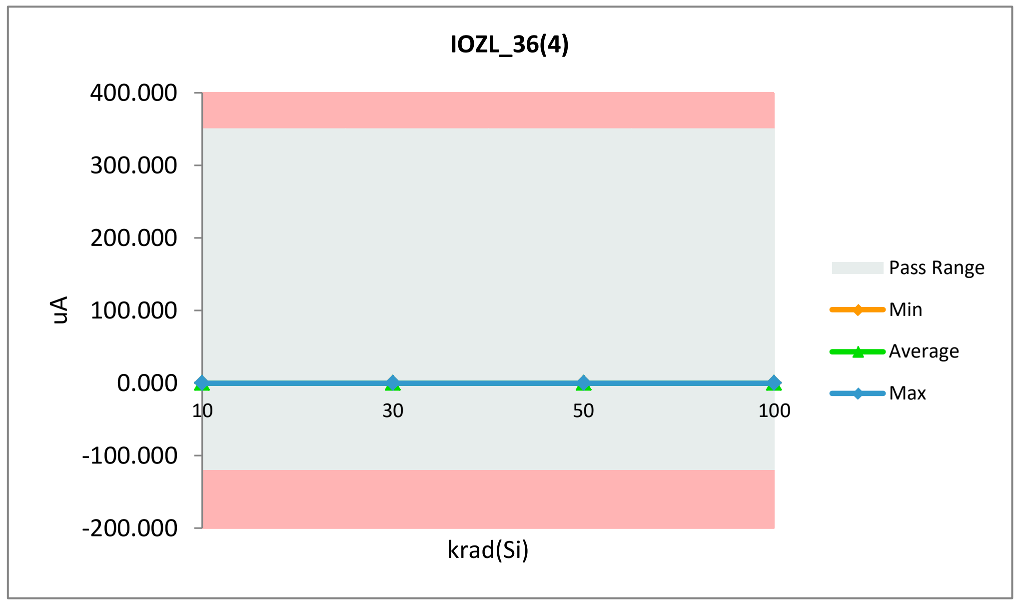


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOZL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.007	-0.020	0.013
10	7	-0.007	-0.020	0.013
10	8	-0.007	-0.001	-0.006
10	9	-0.007	-0.001	-0.006
10	10	-0.007	-0.020	0.013
30	6	-0.019	-0.012	-0.007
30	7	-0.019	-0.012	-0.007
30	8	-0.019	-0.012	-0.007
30	9	-0.019	-0.012	-0.007
30	10	-0.019	-0.012	-0.007
50	16	-0.019	-0.012	-0.007
50	17	-0.019	-0.012	-0.007
50	18	-0.019	-0.012	-0.007
50	19	-0.019	-0.012	-0.007
50	20	-0.019	-0.012	-0.007
100	B043	-0.019	-0.012	-0.007
100	B044	-0.019	-0.031	0.011
100	B045	-0.019	-0.012	-0.007
100	B046	-0.019	-0.012	-0.007
100	B047	-0.019	-0.012	-0.007
100	B048	-0.019	-0.012	-0.007
100	B049	-0.019	-0.012	-0.007
100	B050	-0.019	-0.012	-0.007
100	B051	-0.019	-0.012	-0.007
100	B052	-0.001	-0.012	0.011
100	B053	-0.019	-0.012	-0.007
100	B054	-0.019	-0.031	0.011
100	B055	-0.019	-0.012	-0.007
100	B056	-0.019	-0.012	-0.007
100	B057	-0.019	-0.012	-0.007
100	B058	-0.019	-0.012	-0.007
100	B059	-0.019	-0.012	-0.007
100	B060	-0.019	-0.012	-0.007
100	B061	-0.019	-0.012	-0.007
100	B062	-0.019	-0.008	-0.011
100	B063	-0.019	-0.012	-0.007
100	B064	-0.019	-0.012	-0.007
	Max	-0.001	-0.001	0.013
	Average	-0.017	-0.013	-0.004
	Min	-0.019	-0.031	-0.011
	Std Dev	0.005	0.005	0.007

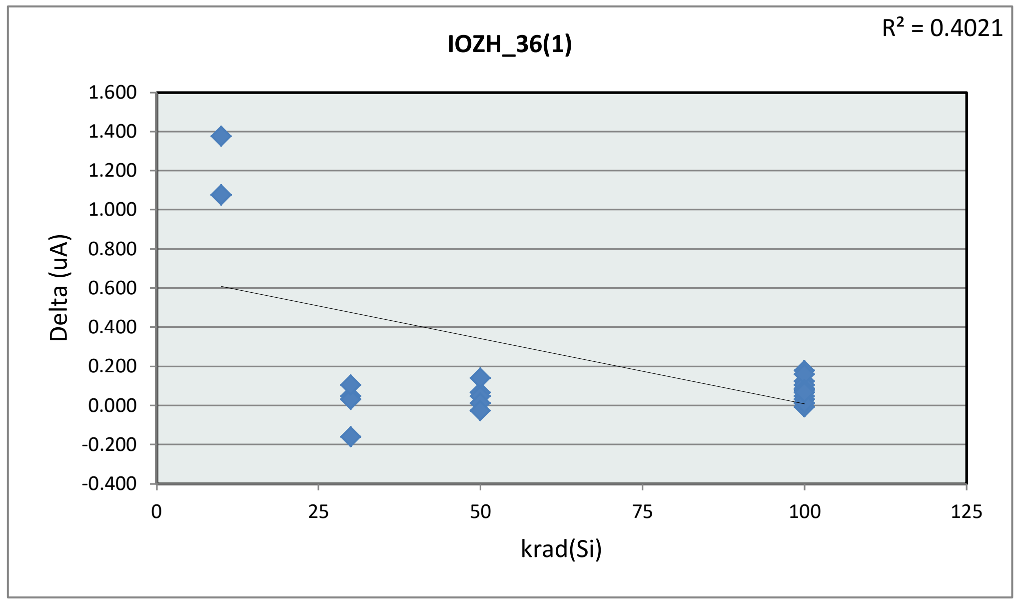


	IOZL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.020	-0.012	-0.012	-0.031
Average	-0.013	-0.012	-0.012	-0.014
Max	-0.001	-0.012	-0.012	-0.008
UL	350.000	350.000	350.000	350.000

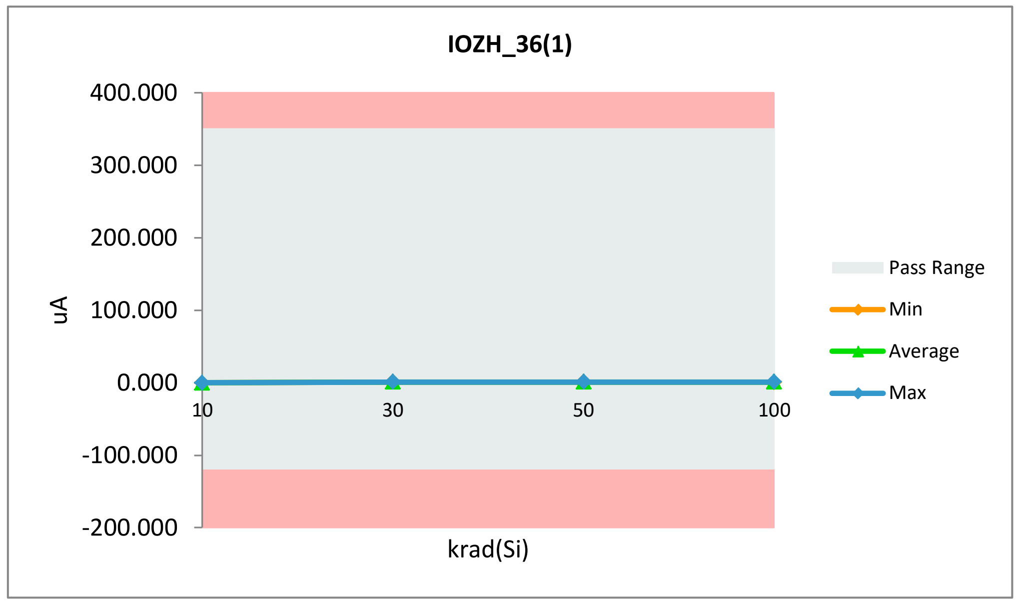


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOZH_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.146	0.071	1.075
10	7	1.146	0.071	1.075
10	8	1.146	0.071	1.075
10	9	1.146	0.071	1.075
10	10	1.446	0.071	1.375
30	6	0.971	0.923	0.048
30	7	0.952	0.923	0.029
30	8	0.952	1.113	-0.161
30	9	0.952	0.923	0.029
30	10	1.026	0.923	0.103
50	16	0.952	0.886	0.066
50	17	1.026	0.979	0.048
50	18	1.045	0.904	0.141
50	19	0.989	0.979	0.010
50	20	0.971	0.997	-0.027
100	B043	0.989	0.812	0.177
100	B044	0.971	0.960	0.010
100	B045	0.989	0.904	0.085
100	B046	0.952	0.942	0.010
100	B047	1.008	0.923	0.085
100	B048	0.989	0.942	0.048
100	B049	0.971	0.979	-0.008
100	B050	1.008	0.886	0.122
100	B051	0.971	0.942	0.029
100	B052	0.971	0.942	0.029
100	B053	1.008	0.904	0.103
100	B054	0.952	0.960	-0.008
100	B055	0.971	0.904	0.066
100	B056	0.952	0.923	0.029
100	B057	0.989	0.960	0.029
100	B058	0.989	0.904	0.085
100	B059	1.008	0.904	0.103
100	B060	0.971	0.904	0.066
100	B061	1.101	0.942	0.159
100	B062	0.989	0.909	0.080
100	B063	0.952	0.942	0.010
100	B064	0.971	0.904	0.066
	Max	1.446	1.113	1.375
	Average	1.014	0.816	0.198
	Min	0.952	0.071	-0.161
	Std Dev	0.094	0.302	0.383



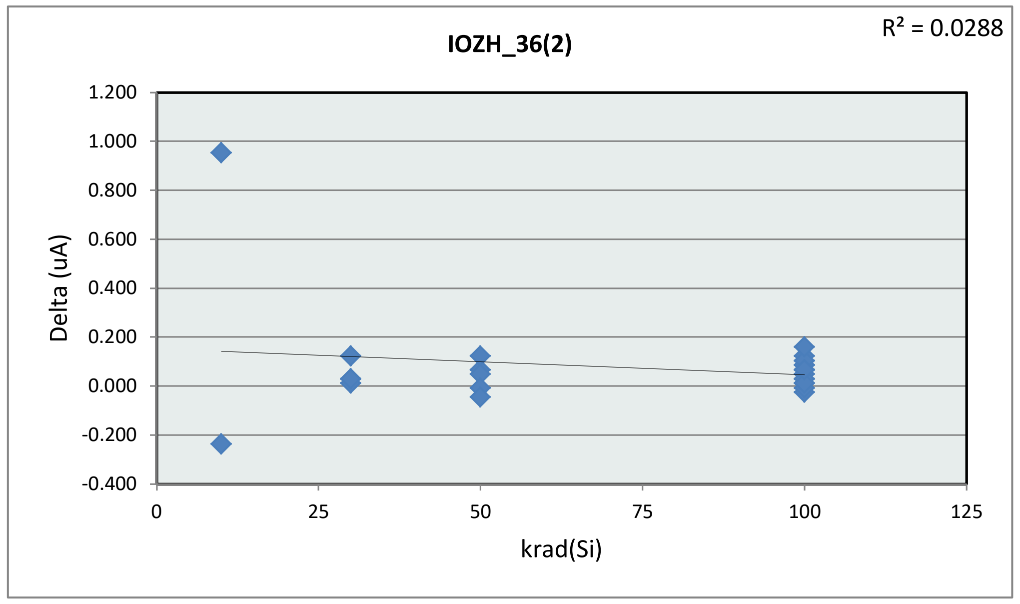
	IOZH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.071	0.923	0.886	0.812
Average	0.071	0.961	0.949	0.922
Max	0.071	1.113	0.997	0.979
UL	350.000	350.000	350.000	350.000



HDR UnBiased TID Report
SN55LVCP22A-SP

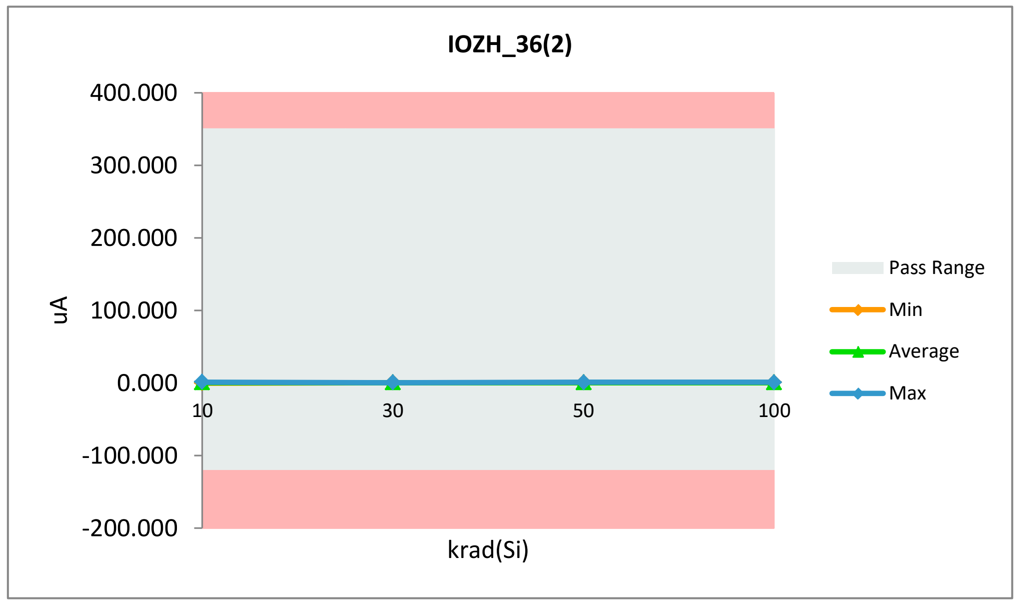
	IOZH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.135	1.373	-0.238
10	7	1.135	0.182	0.953
10	8	1.135	1.373	-0.238
10	9	1.135	0.182	0.953
10	10	1.135	1.373	-0.238
30	6	0.962	0.933	0.029
30	7	0.962	0.933	0.029
30	8	0.944	0.934	0.010
30	9	0.944	0.915	0.029
30	10	1.037	0.915	0.122
50	16	0.944	0.877	0.067
50	17	1.018	0.970	0.048
50	18	1.037	0.915	0.122
50	19	0.981	0.989	-0.008
50	20	0.962	1.008	-0.046
100	B043	1.000	0.934	0.066
100	B044	0.981	0.970	0.011
100	B045	0.981	0.896	0.085
100	B046	0.944	0.933	0.011
100	B047	1.018	0.933	0.085
100	B048	1.000	0.933	0.067
100	B049	0.962	0.989	-0.027
100	B050	1.018	0.896	0.122
100	B051	0.962	0.952	0.011
100	B052	0.981	0.952	0.029
100	B053	1.018	0.915	0.104
100	B054	0.962	0.970	-0.008
100	B055	0.962	0.915	0.048
100	B056	0.962	0.915	0.048
100	B057	1.000	0.970	0.029
100	B058	0.981	0.896	0.085
100	B059	1.000	0.896	0.104
100	B060	0.962	0.896	0.067
100	B061	1.093	0.933	0.160
100	B062	0.981	0.915	0.066
100	B063	0.962	0.952	0.011
100	B064	0.981	0.915	0.067
	Max	1.135	1.373	0.953
	Average	1.005	0.928	0.077
	Min	0.944	0.182	-0.238
	Std Dev	0.061	0.220	0.231



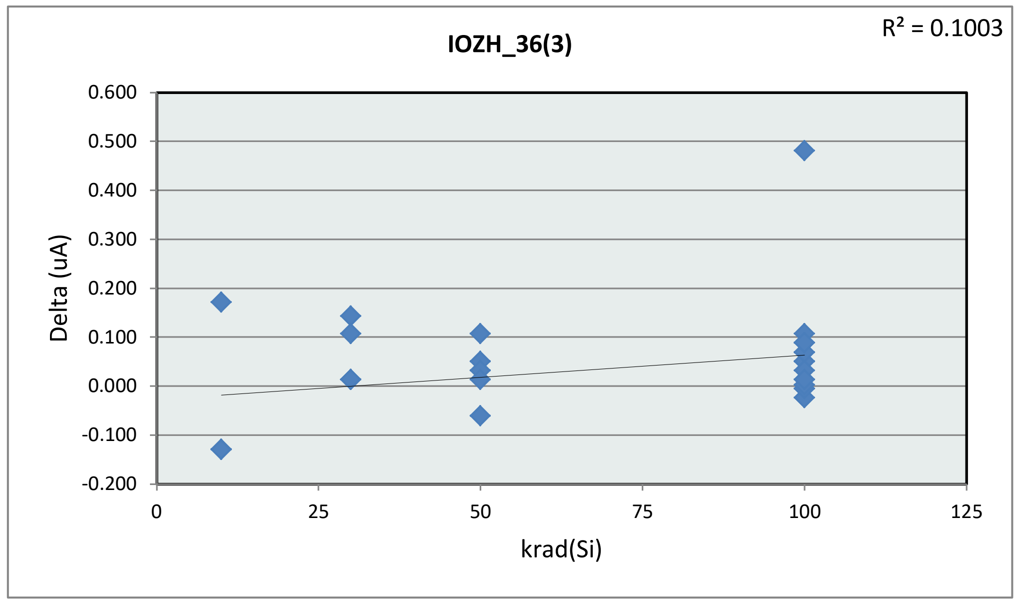
	IOZH_36(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	350	uA
Min Limit	-120	uA

krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.182	0.915	0.877	0.896
Average	0.897	0.926	0.952	0.931
Max	1.373	0.934	1.008	0.989
UL	350.000	350.000	350.000	350.000

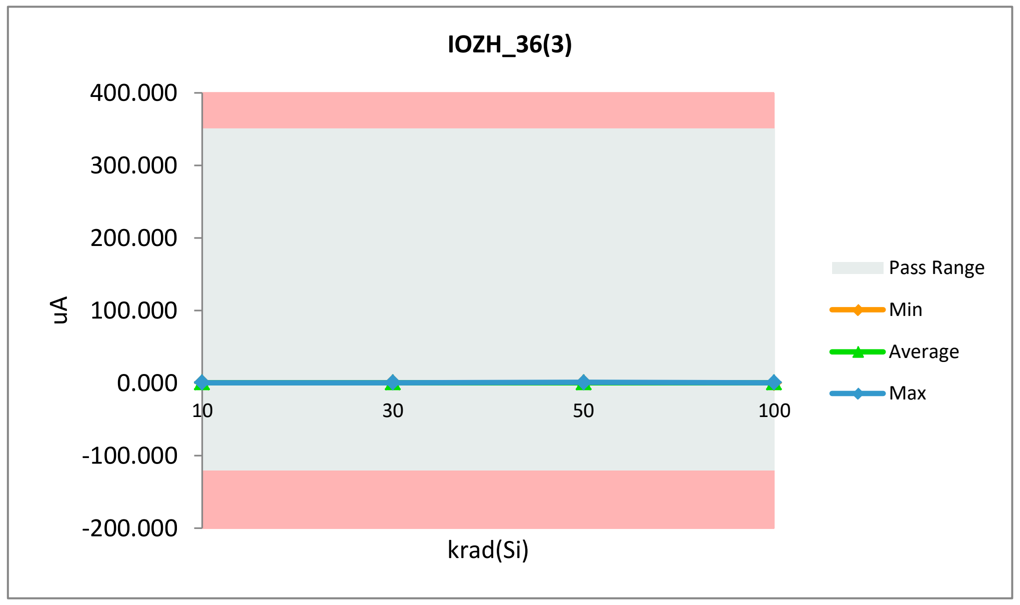


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOZH_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	0.716	0.846	-0.129
10	7	0.716	0.846	-0.129
10	8	0.716	0.846	-0.129
10	9	0.716	0.846	-0.129
10	10	1.017	0.846	0.171
30	6	0.917	0.903	0.013
30	7	0.917	0.903	0.013
30	8	0.917	0.774	0.143
30	9	0.917	0.903	0.013
30	10	1.010	0.903	0.107
50	16	0.917	0.866	0.051
50	17	0.973	0.941	0.032
50	18	1.010	0.903	0.107
50	19	0.954	0.941	0.013
50	20	0.917	0.978	-0.061
100	B043	0.954	0.473	0.481
100	B044	0.917	0.922	-0.005
100	B045	0.954	0.885	0.069
100	B046	0.898	0.922	-0.024
100	B047	0.973	0.903	0.069
100	B048	0.973	0.922	0.051
100	B049	0.917	0.941	-0.024
100	B050	0.973	0.866	0.107
100	B051	0.935	0.922	0.013
100	B052	0.935	0.941	-0.005
100	B053	0.973	0.885	0.088
100	B054	0.917	0.922	-0.005
100	B055	0.917	0.903	0.013
100	B056	0.935	0.885	0.051
100	B057	0.973	0.922	0.051
100	B058	0.954	0.885	0.069
100	B059	0.973	0.885	0.088
100	B060	0.935	0.903	0.032
100	B061	1.010	0.922	0.088
100	B062	0.935	0.933	0.002
100	B063	0.935	0.922	0.013
100	B064	0.973	0.885	0.088
	Max	1.017	0.978	0.481
	Average	0.924	0.886	0.038
	Min	0.716	0.473	-0.129
	Std Dev	0.080	0.080	0.105



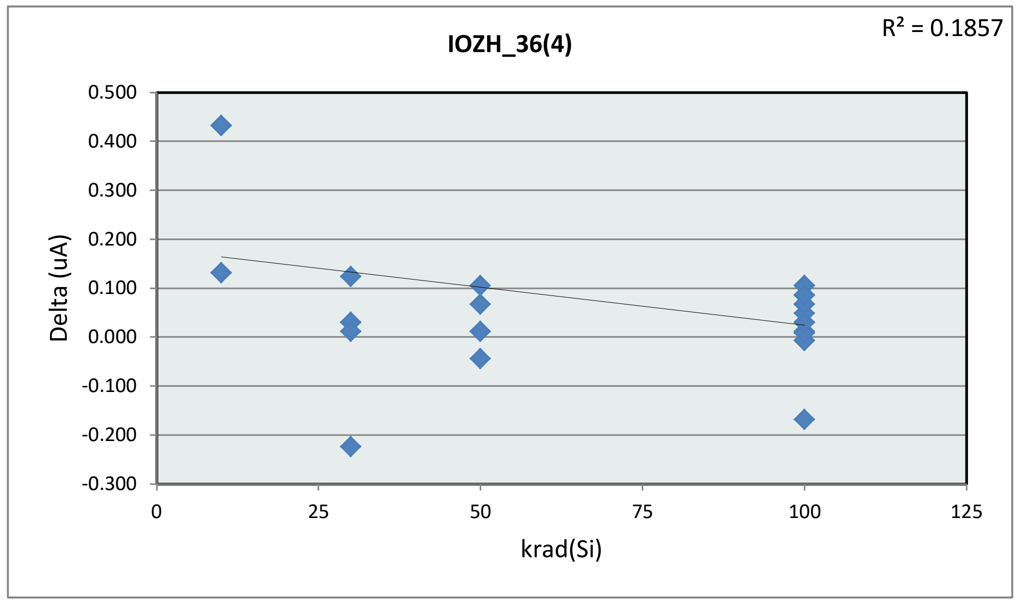
	IOZH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.846	0.774	0.866	0.473
Average	0.846	0.877	0.926	0.888
Max	0.846	0.903	0.978	0.941
UL	350.000	350.000	350.000	350.000



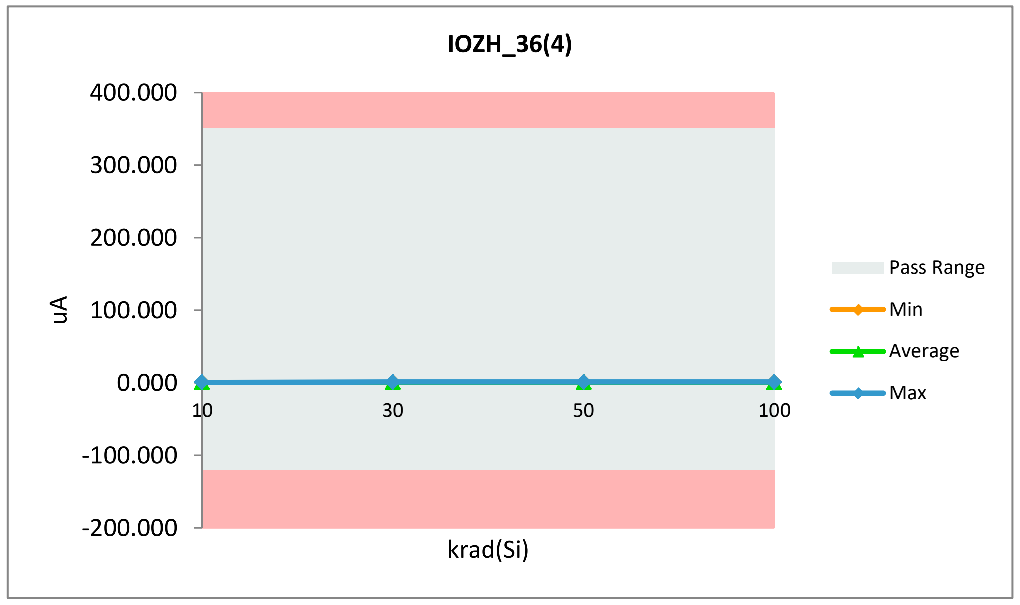
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOZH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.219	0.787	0.432
10	7	0.919	0.787	0.132
10	8	1.219	0.787	0.432
10	9	1.219	0.787	0.432
10	10	0.919	0.787	0.132
30	6	0.948	0.918	0.030
30	7	0.948	0.918	0.030
30	8	0.930	1.154	-0.224
30	9	0.930	0.918	0.012
30	10	1.041	0.918	0.123
50	16	0.948	0.881	0.067
50	17	0.985	0.974	0.012
50	18	1.023	0.918	0.105
50	19	0.967	0.955	0.012
50	20	0.948	0.993	-0.044
100	B043	0.985	1.154	-0.169
100	B044	0.948	0.955	-0.007
100	B045	0.985	0.918	0.067
100	B046	0.930	0.937	-0.007
100	B047	0.985	0.900	0.086
100	B048	1.004	0.937	0.067
100	B049	0.948	0.955	-0.007
100	B050	0.985	0.881	0.105
100	B051	0.967	0.937	0.030
100	B052	0.948	0.955	-0.007
100	B053	0.985	0.900	0.086
100	B054	0.948	0.937	0.012
100	B055	0.948	0.918	0.030
100	B056	0.948	0.918	0.030
100	B057	0.985	0.937	0.049
100	B058	0.967	0.881	0.086
100	B059	1.004	0.900	0.105
100	B060	0.967	0.900	0.067
100	B061	1.041	0.937	0.105
100	B062	0.948	0.940	0.008
100	B063	0.967	0.937	0.030
100	B064	0.985	0.900	0.086
	Max	1.219	1.154	0.432
	Average	0.988	0.919	0.068
	Min	0.919	0.787	-0.224
	Std Dev	0.076	0.078	0.131

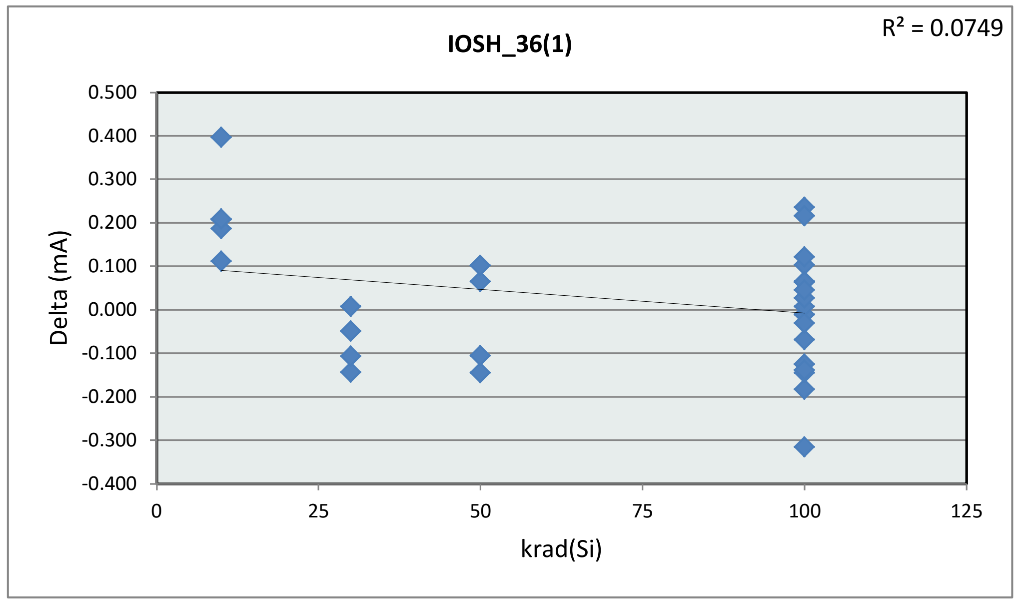


	IOZH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.787	0.918	0.881	0.881
Average	0.787	0.965	0.944	0.933
Max	0.787	1.154	0.993	1.154
UL	350.000	350.000	350.000	350.000

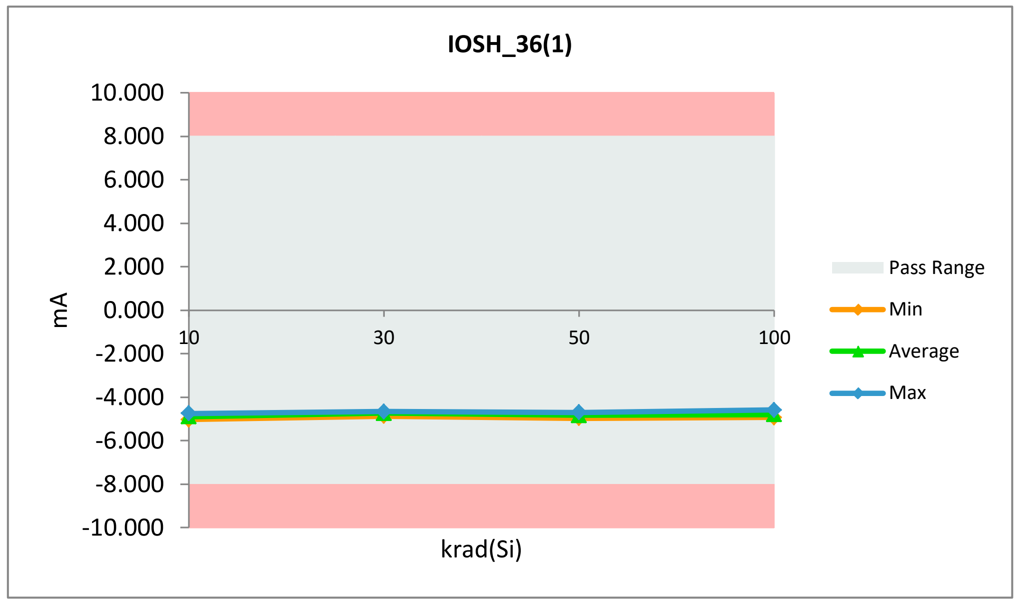


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSH_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-4.557	-4.953	0.396
10	7	-4.765	-4.972	0.207
10	8	-4.595	-4.782	0.187
10	9	-4.633	-4.744	0.111
10	10	-4.822	-5.030	0.208
30	6	-4.656	-4.663	0.007
30	7	-5.016	-4.872	-0.144
30	8	-4.770	-4.663	-0.107
30	9	-4.789	-4.739	-0.050
30	10	-4.808	-4.758	-0.050
50	16	-4.845	-4.701	-0.144
50	17	-4.902	-4.796	-0.106
50	18	-4.789	-4.853	0.064
50	19	-4.864	-4.966	0.102
50	20	-4.713	-4.815	0.102
100	B043	-4.978	-4.663	-0.315
100	B044	-4.732	-4.796	0.064
100	B045	-4.675	-4.739	0.064
100	B046	-4.864	-4.929	0.065
100	B047	-4.864	-4.682	-0.182
100	B048	-4.827	-4.701	-0.126
100	B049	-4.940	-4.929	-0.011
100	B050	-4.845	-4.834	-0.011
100	B051	-4.789	-4.796	0.007
100	B052	-4.637	-4.872	0.235
100	B053	-4.656	-4.872	0.216
100	B054	-4.902	-4.834	-0.068
100	B055	-4.789	-4.891	0.102
100	B056	-4.732	-4.587	-0.145
100	B057	-4.656	-4.720	0.064
100	B058	-4.694	-4.910	0.216
100	B059	-4.751	-4.872	0.121
100	B060	-4.770	-4.796	0.026
100	B061	-4.845	-4.720	-0.125
100	B062	-4.921	-4.782	-0.139
100	B063	-4.827	-4.796	-0.031
100	B064	-4.751	-4.796	0.045
	Max	-4.557	-4.587	0.396
	Average	-4.783	-4.806	0.023
	Min	-5.016	-5.030	-0.315
	Std Dev	0.107	0.102	0.146

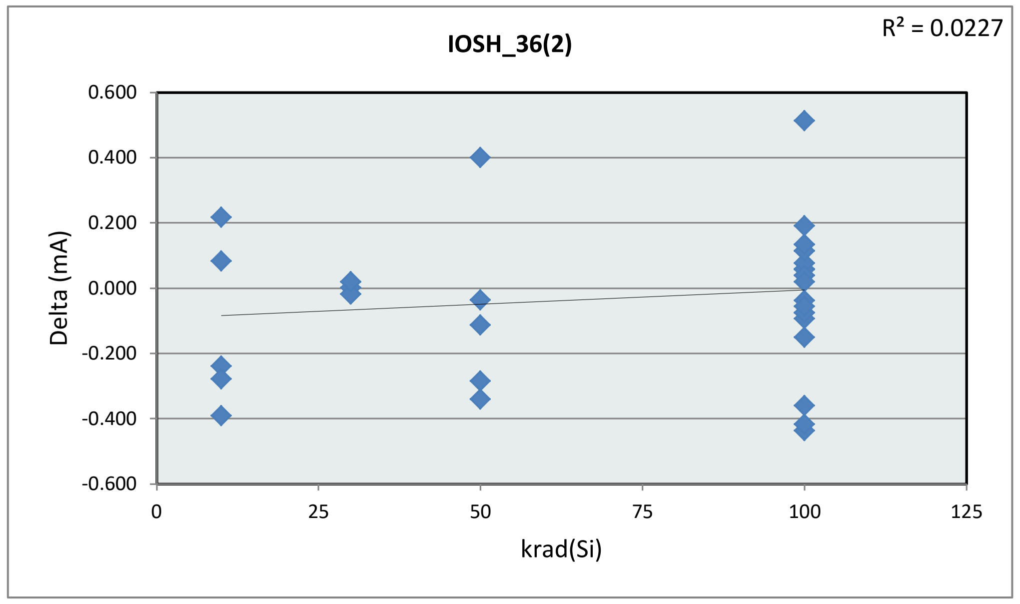


	IOSH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.030	-4.872	-4.966	-4.929
Average	-4.896	-4.739	-4.826	-4.796
Max	-4.744	-4.663	-4.701	-4.587
UL	8.000	8.000	8.000	8.000

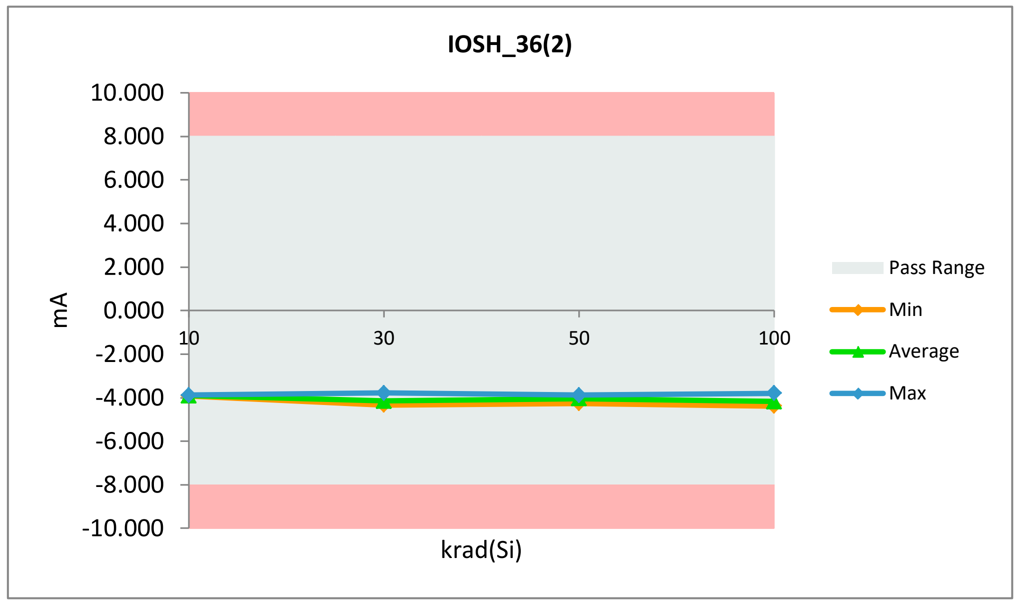


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-4.160	-3.920	-0.240
10	7	-3.799	-3.882	0.083
10	8	-3.685	-3.901	0.216
10	9	-4.198	-3.920	-0.278
10	10	-4.293	-3.901	-0.392
30	6	-3.763	-3.782	0.019
30	7	-4.332	-4.333	0.001
30	8	-4.218	-4.200	-0.018
30	9	-4.237	-4.219	-0.018
30	10	-4.218	-4.238	0.020
50	16	-4.275	-4.238	-0.037
50	17	-3.991	-3.877	-0.114
50	18	-3.858	-4.257	0.399
50	19	-4.313	-3.972	-0.341
50	20	-4.161	-3.877	-0.284
100	B043	-4.313	-4.238	-0.075
100	B044	-3.801	-3.858	0.057
100	B045	-4.123	-4.162	0.039
100	B046	-3.839	-4.352	0.513
100	B047	-4.218	-4.181	-0.037
100	B048	-4.275	-4.124	-0.151
100	B049	-4.294	-4.371	0.077
100	B050	-4.294	-3.858	-0.436
100	B051	-4.256	-3.839	-0.417
100	B052	-4.123	-4.257	0.134
100	B053	-4.180	-4.295	0.115
100	B054	-4.389	-4.295	-0.094
100	B055	-4.199	-4.257	0.058
100	B056	-4.199	-4.124	-0.075
100	B057	-4.161	-3.801	-0.360
100	B058	-4.199	-4.390	0.191
100	B059	-4.161	-4.238	0.077
100	B060	-4.275	-4.219	-0.056
100	B061	-4.161	-4.200	0.039
100	B062	-4.161	-4.275	0.114
100	B063	-4.047	-4.181	0.134
100	B064	-4.256	-4.276	0.020
	Max	-3.685	-3.782	0.513
	Average	-4.147	-4.116	-0.030
	Min	-4.389	-4.390	-0.436
	Std Dev	0.178	0.190	0.211



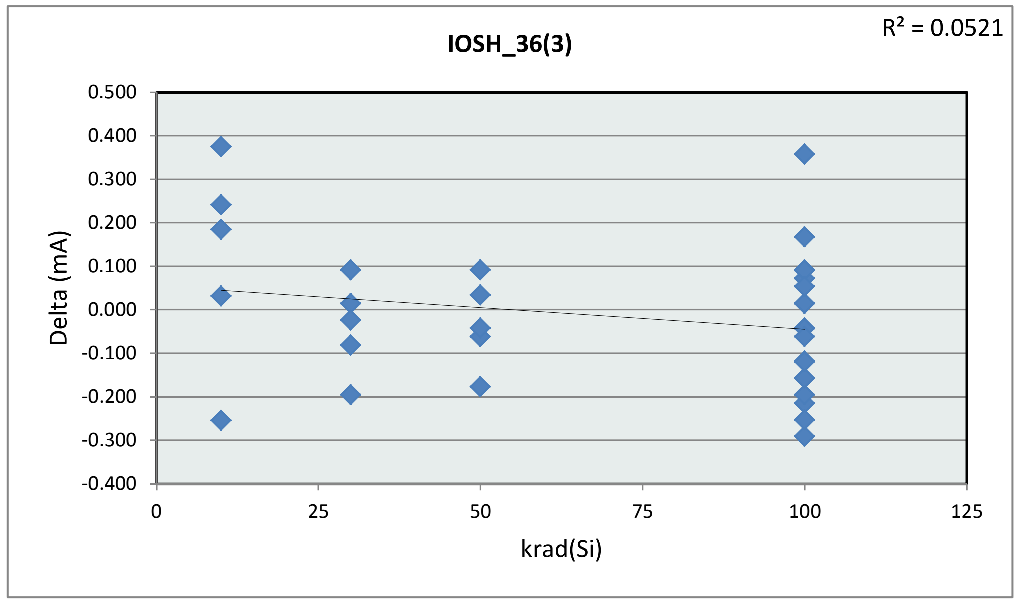
	IOSH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.920	-4.333	-4.257	-4.390
Average	-3.905	-4.154	-4.044	-4.172
Max	-3.882	-3.782	-3.877	-3.801
UL	8.000	8.000	8.000	8.000



HDR UnBiased TID Report
SN55LVCP22A-SP

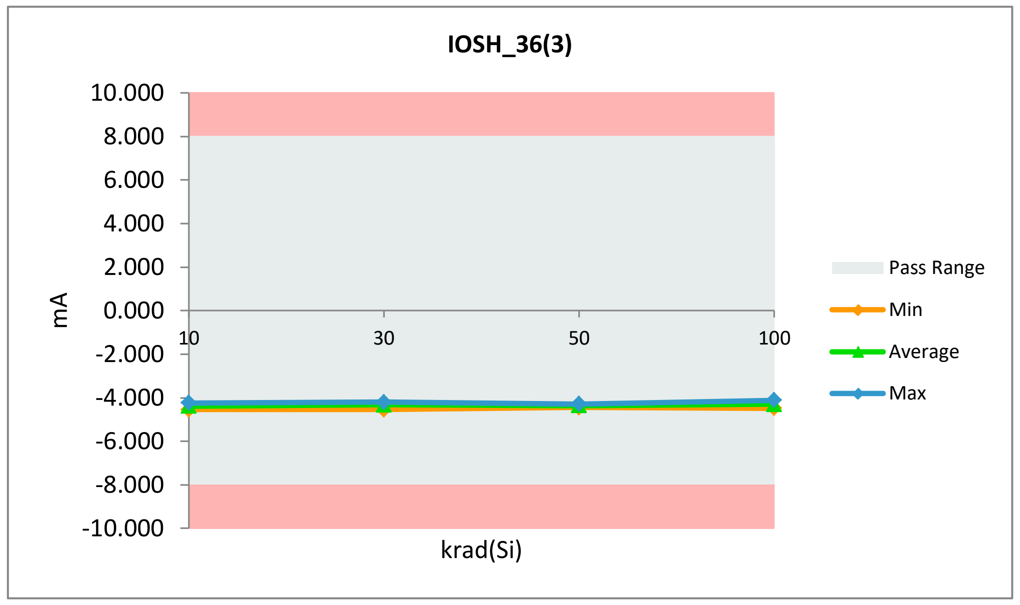
	IOSH_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-4.210	-4.241	0.031
10	7	-4.534	-4.279	-0.255
10	8	-4.058	-4.432	0.374
10	9	-4.248	-4.432	0.184
10	10	-4.305	-4.546	0.241
30	6	-4.278	-4.292	0.014
30	7	-4.564	-4.540	-0.024
30	8	-4.297	-4.216	-0.081
30	9	-4.393	-4.197	-0.196
30	10	-4.278	-4.369	0.091
50	16	-4.431	-4.369	-0.062
50	17	-4.469	-4.292	-0.177
50	18	-4.297	-4.388	0.091
50	19	-4.412	-4.445	0.033
50	20	-4.354	-4.312	-0.042
100	B043	-4.450	-4.235	-0.215
100	B044	-4.373	-4.254	-0.119
100	B045	-4.145	-4.159	0.014
100	B046	-4.393	-4.350	-0.043
100	B047	-4.335	-4.292	-0.043
100	B048	-4.297	-4.140	-0.157
100	B049	-4.469	-4.483	0.014
100	B050	-4.335	-4.407	0.072
100	B051	-4.545	-4.254	-0.291
100	B052	-4.335	-4.407	0.072
100	B053	-4.107	-4.464	0.357
100	B054	-4.469	-4.350	-0.119
100	B055	-4.335	-4.426	0.091
100	B056	-4.278	-4.292	0.014
100	B057	-4.316	-4.121	-0.195
100	B058	-4.354	-4.445	0.091
100	B059	-4.183	-4.350	0.167
100	B060	-4.335	-4.273	-0.062
100	B061	-4.431	-4.178	-0.253
100	B062	-4.393	-4.235	-0.158
100	B063	-4.354	-4.235	-0.119
100	B064	-4.278	-4.331	0.053
	Max	-4.058	-4.121	0.374
	Average	-4.342	-4.325	-0.016
	Min	-4.564	-4.546	-0.291
	Std Dev	0.114	0.109	0.159



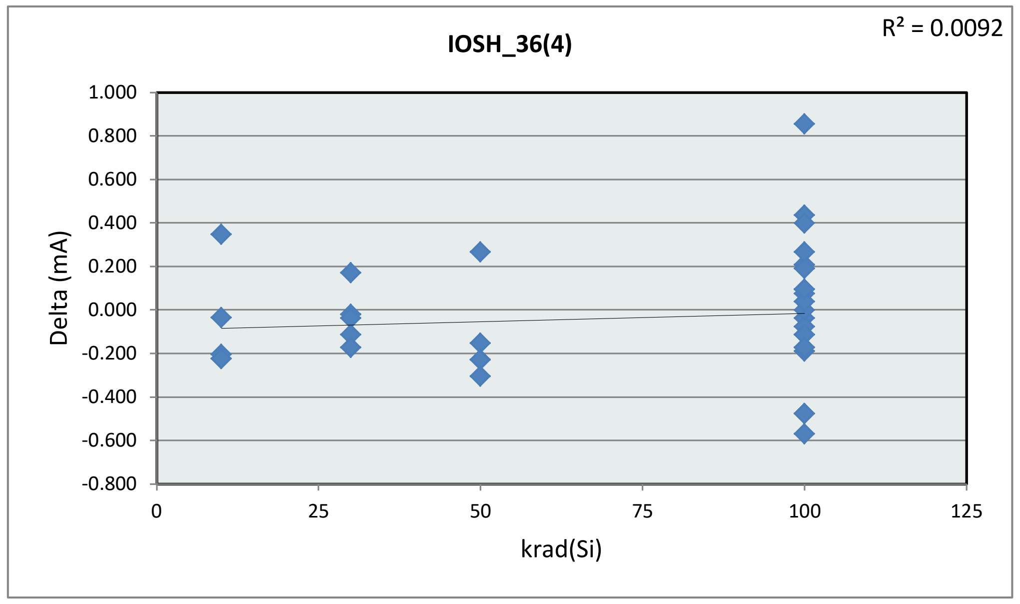
	IOSH_36(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.546	-4.540	-4.445	-4.483
Average	-4.386	-4.323	-4.361	-4.304
Max	-4.241	-4.197	-4.292	-4.121
UL	8.000	8.000	8.000	8.000

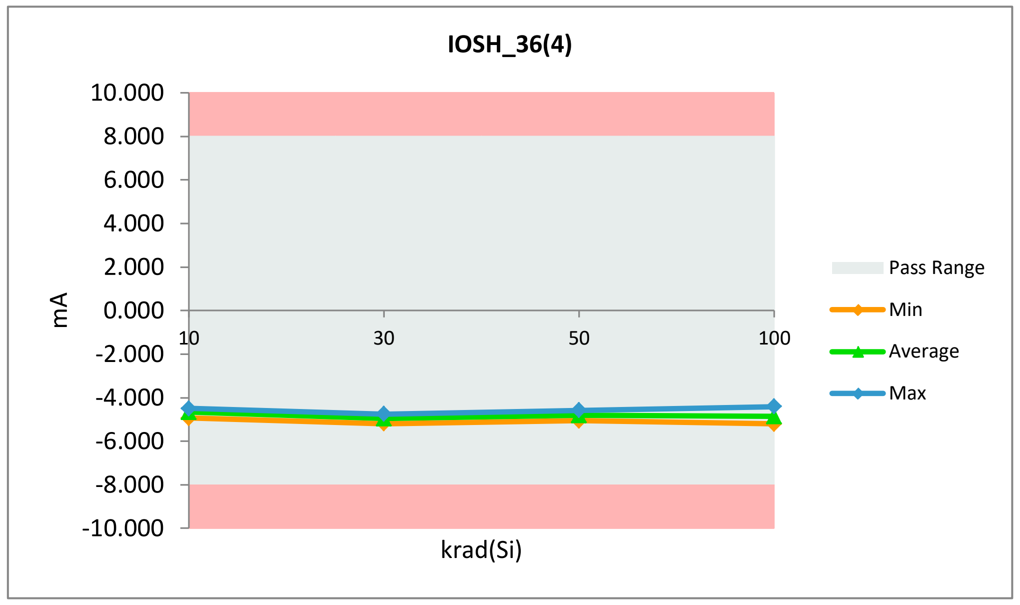


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSH_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-4.838	-4.613	-0.225
10	7	-4.914	-4.708	-0.206
10	8	-4.724	-4.499	-0.225
10	9	-4.591	-4.556	-0.035
10	10	-4.591	-4.937	0.346
30	6	-4.942	-4.922	-0.020
30	7	-5.227	-5.188	-0.039
30	8	-4.866	-4.751	-0.115
30	9	-5.056	-4.884	-0.172
30	10	-4.885	-5.055	0.170
50	16	-4.790	-5.055	0.265
50	17	-5.094	-4.865	-0.229
50	18	-4.923	-4.770	-0.153
50	19	-4.999	-4.770	-0.229
50	20	-4.885	-4.580	-0.305
100	B043	-4.980	-4.409	-0.571
100	B044	-4.942	-4.903	-0.039
100	B045	-4.410	-4.846	0.436
100	B046	-5.056	-4.979	-0.077
100	B047	-4.885	-4.960	0.075
100	B048	-4.923	-4.447	-0.476
100	B049	-5.189	-4.713	-0.476
100	B050	-4.638	-5.036	0.398
100	B051	-5.075	-4.884	-0.191
100	B052	-4.923	-4.922	-0.001
100	B053	-4.353	-5.207	0.854
100	B054	-5.113	-4.637	-0.476
100	B055	-4.999	-5.093	0.094
100	B056	-4.885	-4.922	0.037
100	B057	-4.752	-4.637	-0.115
100	B058	-4.904	-5.112	0.208
100	B059	-4.847	-5.036	0.189
100	B060	-4.657	-4.922	0.265
100	B061	-4.657	-4.751	0.094
100	B062	-5.037	-4.923	-0.114
100	B063	-4.999	-4.827	-0.172
100	B064	-4.885	-4.713	-0.172
	Max	-4.353	-4.409	0.854
	Average	-4.877	-4.839	-0.038
	Min	-5.227	-5.207	-0.571
	Std Dev	0.196	0.202	0.287

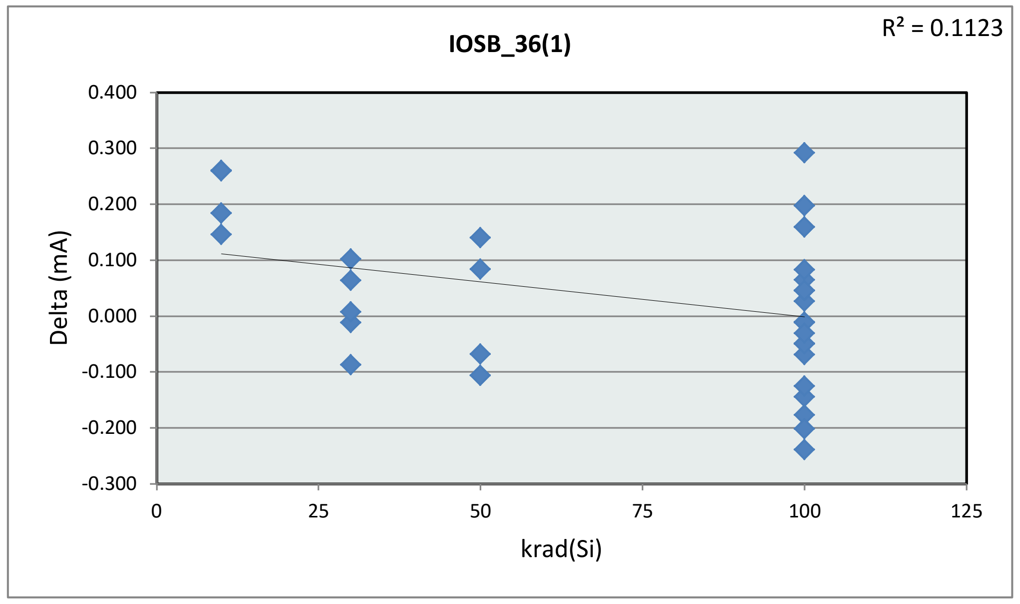


	IOSH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.937	-5.188	-5.055	-5.207
Average	-4.663	-4.960	-4.808	-4.858
Max	-4.499	-4.751	-4.580	-4.409
UL	8.000	8.000	8.000	8.000

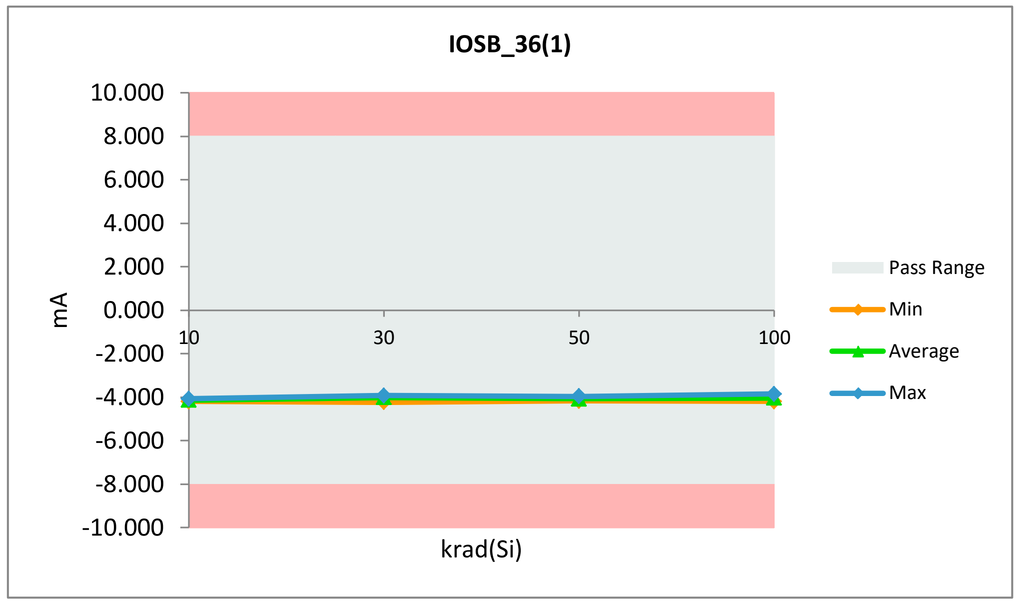


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-3.950	-4.134	0.184
10	7	-3.893	-4.153	0.260
10	8	-3.856	-4.115	0.259
10	9	-3.893	-4.077	0.184
10	10	-4.045	-4.191	0.146
30	6	-3.860	-3.924	0.064
30	7	-4.126	-4.227	0.101
30	8	-3.936	-3.924	-0.012
30	9	-3.993	-4.000	0.007
30	10	-4.088	-4.000	-0.088
50	16	-4.069	-3.962	-0.107
50	17	-4.145	-4.076	-0.069
50	18	-4.107	-4.000	-0.107
50	19	-4.031	-4.171	0.140
50	20	-4.069	-4.152	0.083
100	B043	-4.031	-3.962	-0.069
100	B044	-3.879	-4.076	0.197
100	B045	-3.993	-4.019	0.026
100	B046	-4.031	-4.076	0.045
100	B047	-4.126	-3.886	-0.240
100	B048	-4.163	-4.019	-0.144
100	B049	-4.031	-4.190	0.159
100	B050	-4.163	-4.114	-0.049
100	B051	-3.955	-4.152	0.197
100	B052	-3.841	-4.133	0.292
100	B053	-3.974	-4.019	0.045
100	B054	-4.201	-4.190	-0.011
100	B055	-4.012	-4.076	0.064
100	B056	-3.898	-3.848	-0.050
100	B057	-4.012	-4.000	-0.012
100	B058	-3.974	-4.133	0.159
100	B059	-3.955	-4.038	0.083
100	B060	-3.974	-3.943	-0.031
100	B061	-4.107	-3.981	-0.126
100	B062	-4.182	-4.005	-0.177
100	B063	-4.126	-3.924	-0.202
100	B064	-3.955	-4.000	0.045
	Max	-3.841	-3.848	0.292
	Average	-4.017	-4.051	0.034
	Min	-4.201	-4.227	-0.240
	Std Dev	0.100	0.096	0.136

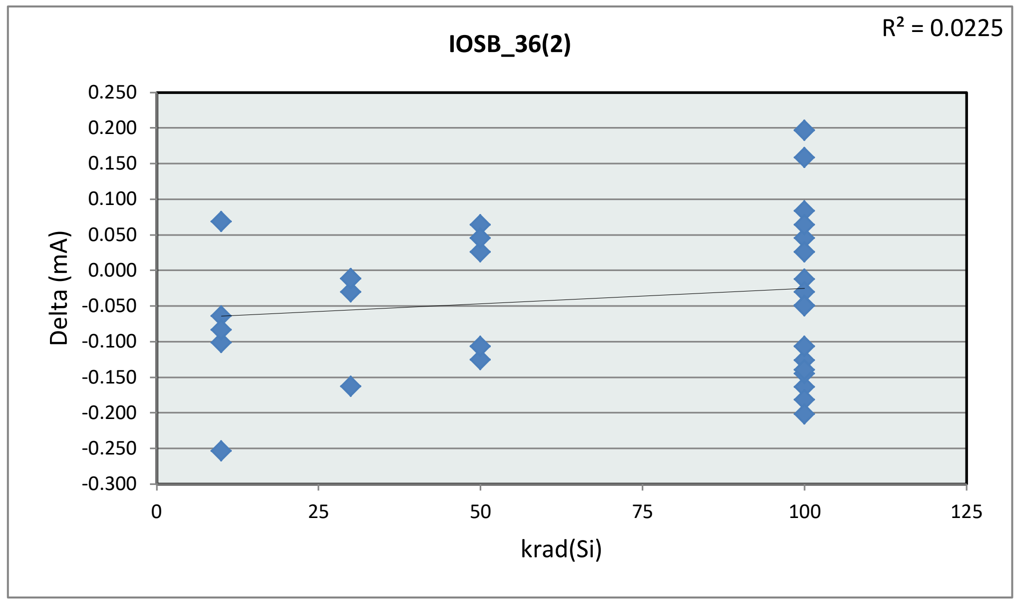


	IOSB_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.191	-4.227	-4.171	-4.190
Average	-4.134	-4.015	-4.072	-4.036
Max	-4.077	-3.924	-3.962	-3.848
UL	8.000	8.000	8.000	8.000

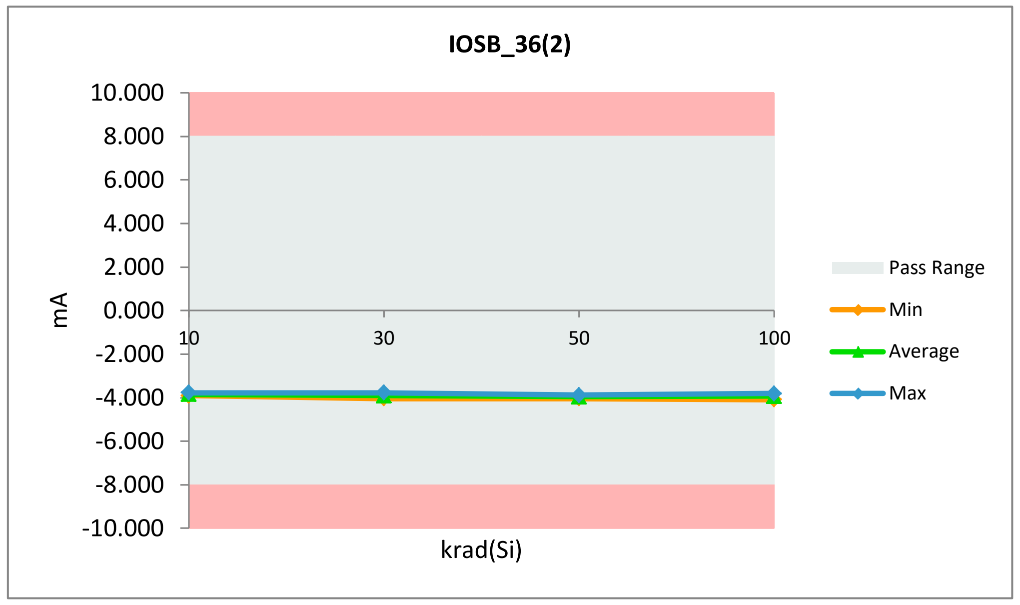


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-3.818	-3.886	0.068
10	7	-3.893	-3.829	-0.064
10	8	-3.931	-3.829	-0.102
10	9	-3.856	-3.772	-0.084
10	10	-4.159	-3.905	-0.254
30	6	-3.841	-3.811	-0.030
30	7	-4.050	-4.038	-0.012
30	8	-3.936	-3.773	-0.163
30	9	-3.955	-3.943	-0.012
30	10	-3.974	-3.962	-0.012
50	16	-4.012	-3.886	-0.126
50	17	-4.031	-3.924	-0.107
50	18	-3.974	-4.000	0.026
50	19	-3.974	-4.038	0.064
50	20	-3.917	-3.962	0.045
100	B043	-4.012	-3.848	-0.164
100	B044	-3.822	-3.981	0.159
100	B045	-3.879	-3.867	-0.012
100	B046	-4.126	-4.019	-0.107
100	B047	-3.993	-3.811	-0.182
100	B048	-3.974	-3.848	-0.126
100	B049	-3.993	-4.076	0.083
100	B050	-4.126	-4.095	-0.031
100	B051	-3.955	-3.981	0.026
100	B052	-3.804	-4.000	0.196
100	B053	-4.050	-4.000	-0.050
100	B054	-4.050	-4.000	-0.050
100	B055	-3.936	-3.981	0.045
100	B056	-3.860	-3.811	-0.049
100	B057	-4.031	-3.829	-0.202
100	B058	-3.860	-4.057	0.197
100	B059	-3.898	-3.962	0.064
100	B060	-3.936	-3.886	-0.050
100	B061	-3.993	-3.848	-0.145
100	B062	-4.031	-3.891	-0.140
100	B063	-3.993	-3.886	-0.107
100	B064	-3.917	-3.943	0.026
	Max	-3.804	-3.772	0.197
	Average	-3.961	-3.924	-0.037
	Min	-4.159	-4.095	-0.254
	Std Dev	0.087	0.089	0.107



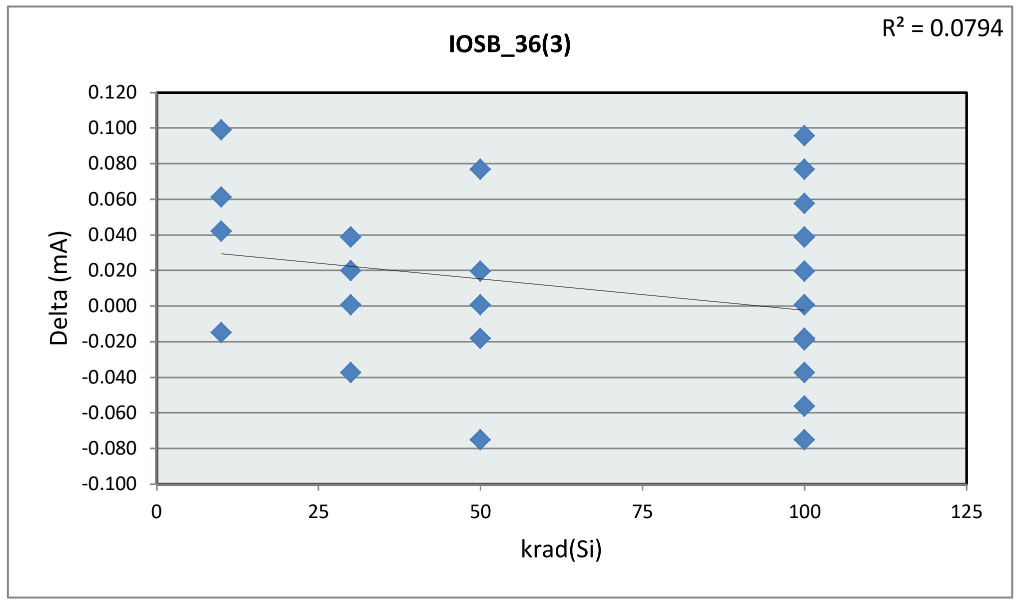
	IOSB_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.905	-4.038	-4.038	-4.095
Average	-3.844	-3.905	-3.962	-3.937
Max	-3.772	-3.773	-3.886	-3.811
UL	8.000	8.000	8.000	8.000



HDR UnBiased TID Report
SN55LVCP22A-SP

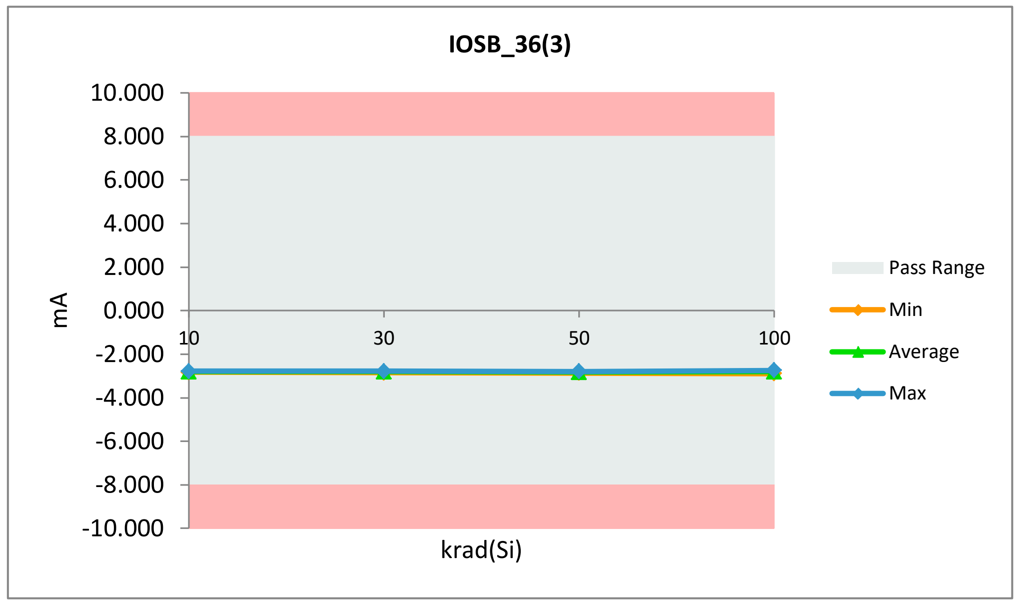
	IOSB_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-2.736	-2.778	0.042
10	7	-2.755	-2.797	0.042
10	8	-2.736	-2.835	0.099
10	9	-2.755	-2.816	0.061
10	10	-2.812	-2.797	-0.015
30	6	-2.756	-2.795	0.039
30	7	-2.832	-2.852	0.020
30	8	-2.794	-2.795	0.001
30	9	-2.813	-2.776	-0.037
30	10	-2.775	-2.814	0.039
50	16	-2.813	-2.795	-0.018
50	17	-2.889	-2.814	-0.075
50	18	-2.794	-2.814	0.020
50	19	-2.870	-2.871	0.001
50	20	-2.756	-2.833	0.077
100	B043	-2.851	-2.814	-0.037
100	B044	-2.794	-2.738	-0.056
100	B045	-2.756	-2.757	0.001
100	B046	-2.794	-2.852	0.058
100	B047	-2.794	-2.795	0.001
100	B048	-2.794	-2.757	-0.037
100	B049	-2.813	-2.890	0.077
100	B050	-2.813	-2.795	-0.018
100	B051	-2.813	-2.795	-0.018
100	B052	-2.756	-2.795	0.039
100	B053	-2.794	-2.833	0.039
100	B054	-2.870	-2.814	-0.056
100	B055	-2.794	-2.814	0.020
100	B056	-2.794	-2.738	-0.056
100	B057	-2.775	-2.795	0.020
100	B058	-2.794	-2.890	0.096
100	B059	-2.775	-2.814	0.039
100	B060	-2.832	-2.814	-0.018
100	B061	-2.889	-2.814	-0.075
100	B062	-2.889	-2.870	-0.019
100	B063	-2.794	-2.795	0.001
100	B064	-2.832	-2.833	0.001
	Max	-2.736	-2.738	0.099
	Average	-2.803	-2.811	0.008
	Min	-2.889	-2.890	-0.075
	Std Dev	0.042	0.036	0.046



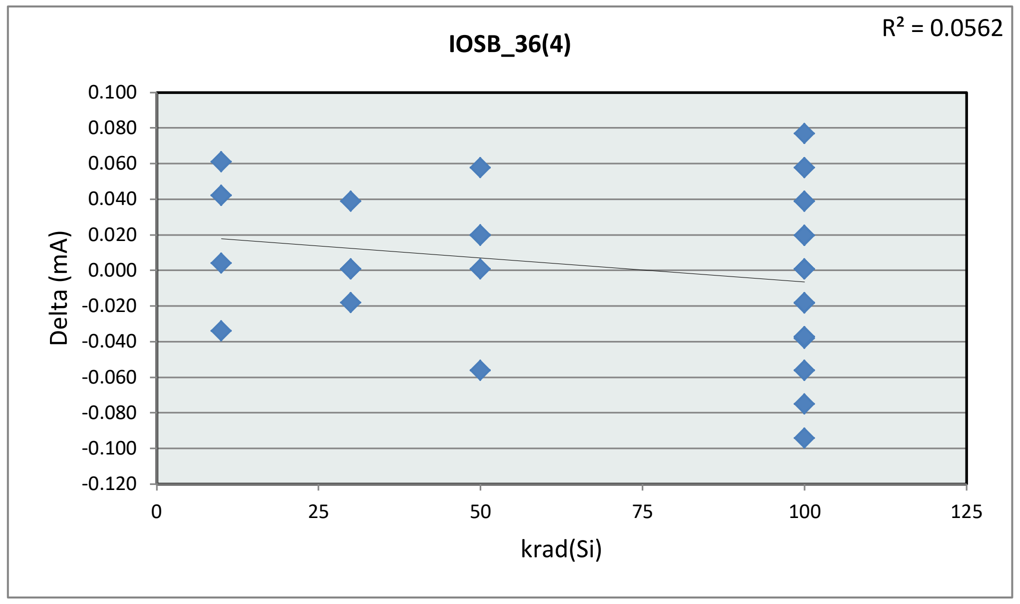
	IOSB_36(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.835	-2.852	-2.871	-2.890
Average	-2.805	-2.806	-2.825	-2.810
Max	-2.778	-2.776	-2.795	-2.738
UL	8.000	8.000	8.000	8.000

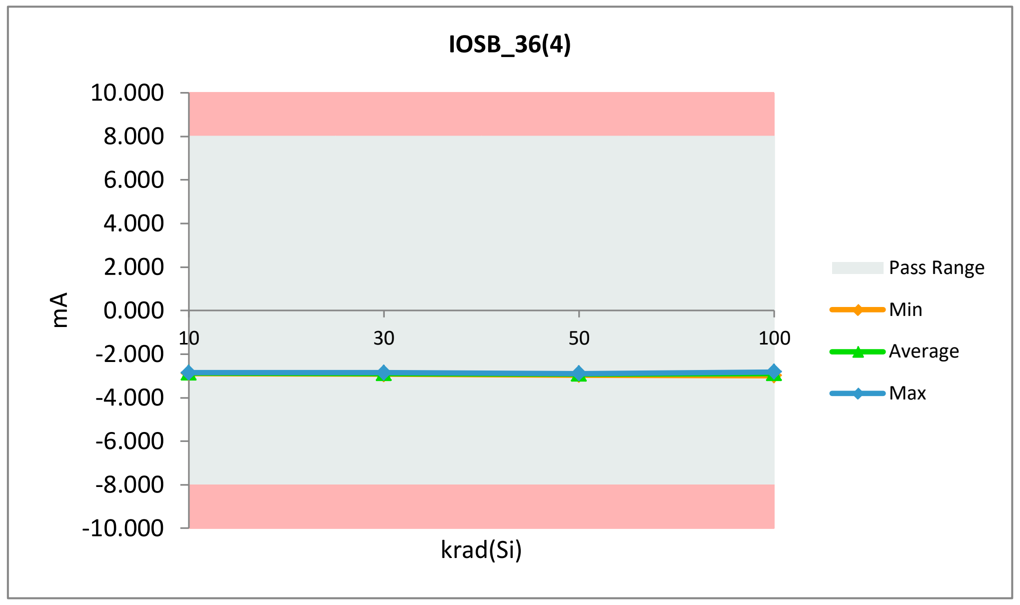


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-2.831	-2.873	0.042
10	7	-2.850	-2.854	0.004
10	8	-2.793	-2.854	0.061
10	9	-2.850	-2.892	0.042
10	10	-2.907	-2.873	-0.034
30	6	-2.851	-2.852	0.001
30	7	-2.927	-2.928	0.001
30	8	-2.870	-2.871	0.001
30	9	-2.889	-2.871	-0.018
30	10	-2.870	-2.909	0.039
50	16	-2.889	-2.890	0.001
50	17	-2.965	-2.909	-0.056
50	18	-2.889	-2.909	0.020
50	19	-2.946	-2.966	0.020
50	20	-2.832	-2.890	0.058
100	B043	-2.965	-2.890	-0.075
100	B044	-2.851	-2.890	0.039
100	B045	-2.832	-2.814	-0.018
100	B046	-2.889	-2.947	0.058
100	B047	-2.832	-2.852	0.020
100	B048	-2.870	-2.833	-0.037
100	B049	-2.908	-2.985	0.077
100	B050	-2.908	-2.890	-0.018
100	B051	-2.889	-2.890	0.001
100	B052	-2.832	-2.871	0.039
100	B053	-2.889	-2.909	0.020
100	B054	-2.965	-2.909	-0.056
100	B055	-2.870	-2.890	0.020
100	B056	-2.870	-2.833	-0.037
100	B057	-2.889	-2.890	0.001
100	B058	-2.889	-2.947	0.058
100	B059	-2.870	-2.871	0.001
100	B060	-2.927	-2.871	-0.056
100	B061	-2.965	-2.871	-0.094
100	B062	-2.965	-2.927	-0.038
100	B063	-2.889	-2.852	-0.037
100	B064	-2.927	-2.928	0.001
	Max	-2.793	-2.814	0.077
	Average	-2.888	-2.889	0.001
	Min	-2.965	-2.985	-0.094
	Std Dev	0.044	0.037	0.041

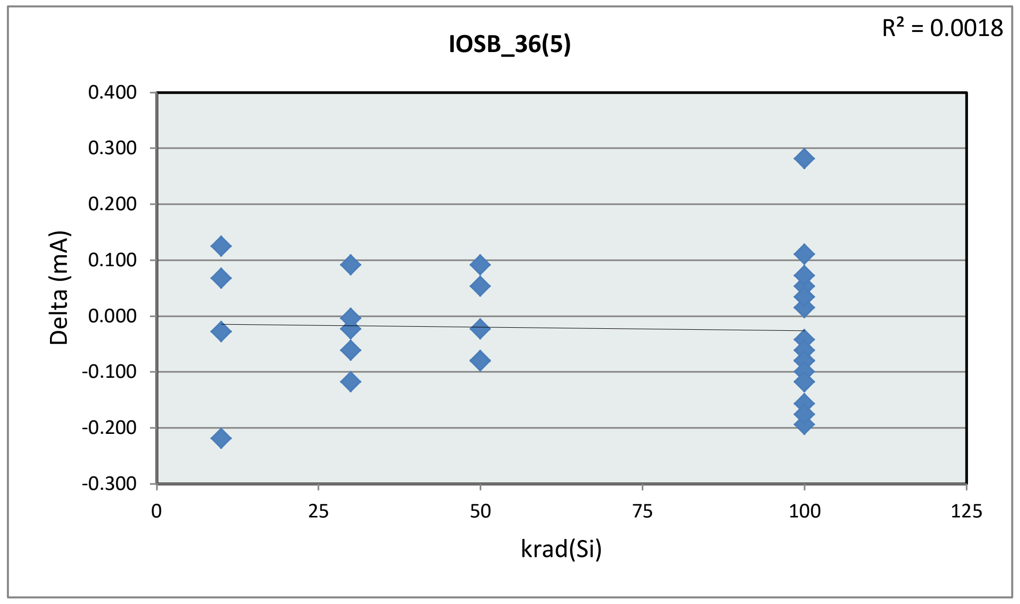


	IOSB_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.892	-2.928	-2.966	-2.985
Average	-2.869	-2.886	-2.913	-2.889
Max	-2.854	-2.852	-2.890	-2.814
UL	8.000	8.000	8.000	8.000

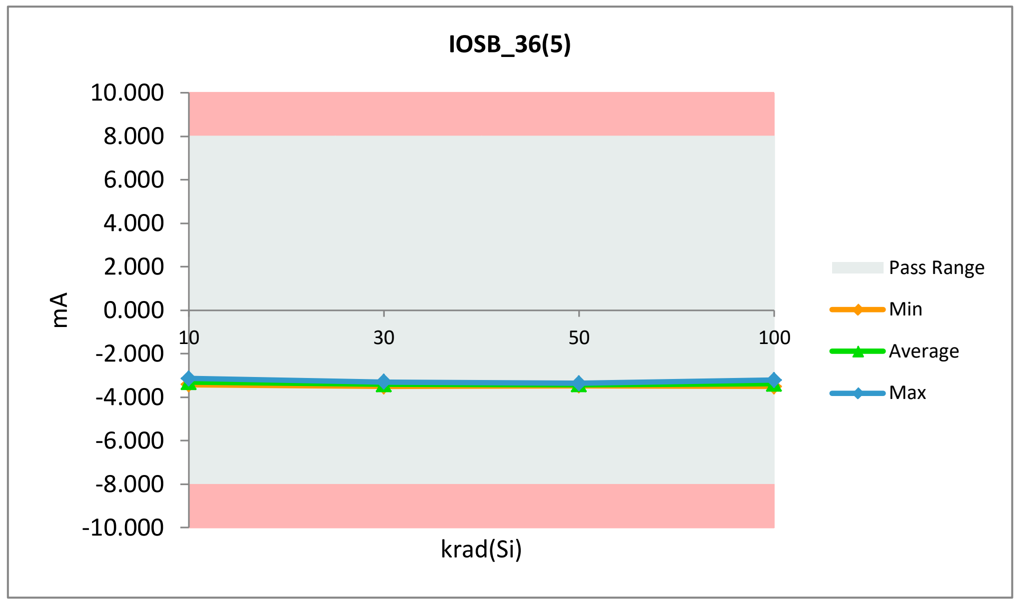


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-3.354	-3.135	-0.219
10	7	-3.335	-3.307	-0.028
10	8	-3.220	-3.345	0.125
10	9	-3.392	-3.364	-0.028
10	10	-3.354	-3.421	0.067
30	6	-3.421	-3.398	-0.023
30	7	-3.516	-3.512	-0.004
30	8	-3.364	-3.302	-0.062
30	9	-3.478	-3.360	-0.118
30	10	-3.364	-3.455	0.091
50	16	-3.497	-3.474	-0.023
50	17	-3.440	-3.360	-0.080
50	18	-3.383	-3.474	0.091
50	19	-3.516	-3.436	-0.080
50	20	-3.326	-3.379	0.053
100	B043	-3.440	-3.264	-0.176
100	B044	-3.402	-3.322	-0.080
100	B045	-3.269	-3.322	0.053
100	B046	-3.402	-3.455	0.053
100	B047	-3.364	-3.398	0.034
100	B048	-3.383	-3.226	-0.157
100	B049	-3.516	-3.474	-0.042
100	B050	-3.383	-3.398	0.015
100	B051	-3.516	-3.322	-0.194
100	B052	-3.440	-3.379	-0.061
100	B053	-3.231	-3.512	0.281
100	B054	-3.516	-3.398	-0.118
100	B055	-3.440	-3.512	0.072
100	B056	-3.402	-3.417	0.015
100	B057	-3.269	-3.207	-0.062
100	B058	-3.402	-3.512	0.110
100	B059	-3.345	-3.455	0.110
100	B060	-3.478	-3.398	-0.080
100	B061	-3.459	-3.283	-0.176
100	B062	-3.440	-3.340	-0.100
100	B063	-3.459	-3.341	-0.118
100	B064	-3.440	-3.474	0.034
	Max	-3.220	-3.135	0.281
	Average	-3.404	-3.382	-0.022
	Min	-3.516	-3.512	-0.219
	Std Dev	0.079	0.090	0.106



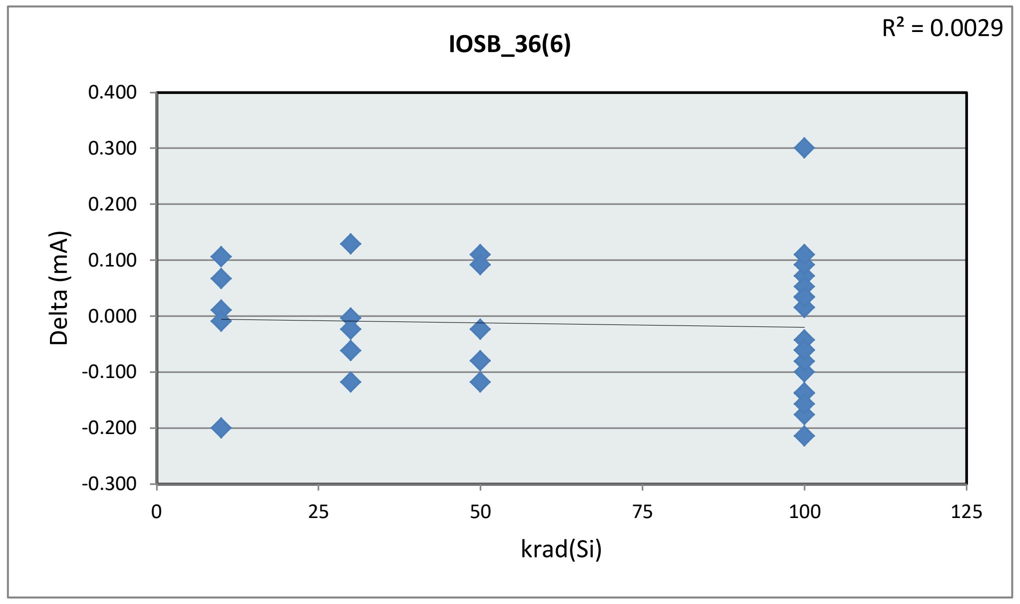
	IOSB_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.421	-3.512	-3.474	-3.512
Average	-3.314	-3.405	-3.425	-3.382
Max	-3.135	-3.302	-3.360	-3.207
UL	8.000	8.000	8.000	8.000



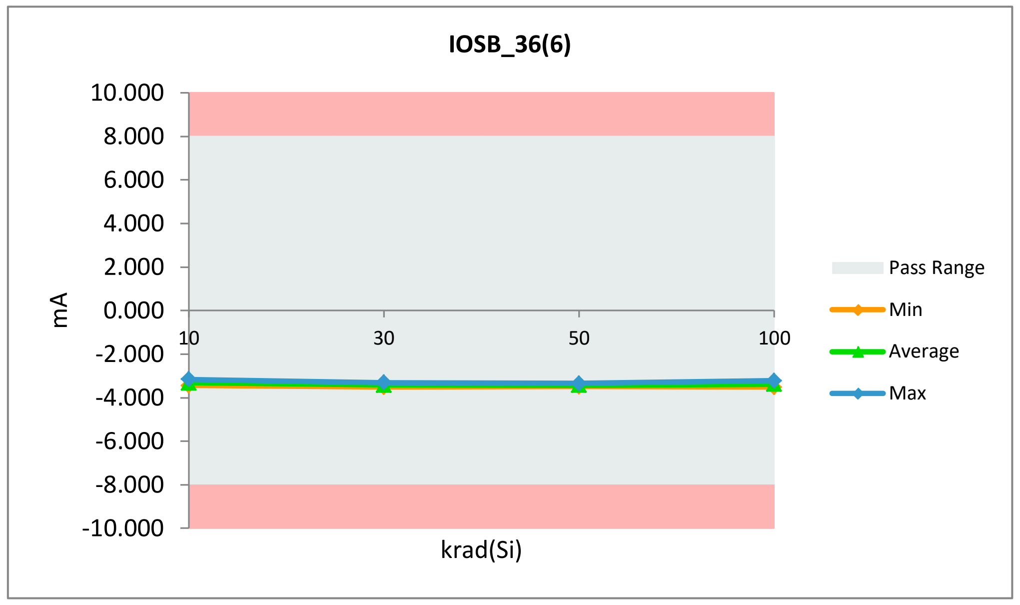
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOSB_36(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-3.354	-3.154	-0.200
10	7	-3.296	-3.307	0.011
10	8	-3.220	-3.326	0.106
10	9	-3.392	-3.383	-0.009
10	10	-3.373	-3.440	0.067
30	6	-3.421	-3.417	-0.004
30	7	-3.535	-3.512	-0.023
30	8	-3.364	-3.302	-0.062
30	9	-3.478	-3.360	-0.118
30	10	-3.345	-3.474	0.129
50	16	-3.497	-3.474	-0.023
50	17	-3.459	-3.341	-0.118
50	18	-3.383	-3.493	0.110
50	19	-3.516	-3.436	-0.080
50	20	-3.307	-3.398	0.091
100	B043	-3.459	-3.283	-0.176
100	B044	-3.402	-3.302	-0.100
100	B045	-3.231	-3.302	0.071
100	B046	-3.421	-3.436	0.015
100	B047	-3.307	-3.398	0.091
100	B048	-3.383	-3.245	-0.138
100	B049	-3.516	-3.455	-0.061
100	B050	-3.383	-3.417	0.034
100	B051	-3.516	-3.302	-0.214
100	B052	-3.440	-3.379	-0.061
100	B053	-3.212	-3.512	0.300
100	B054	-3.516	-3.379	-0.137
100	B055	-3.459	-3.512	0.053
100	B056	-3.421	-3.436	0.015
100	B057	-3.269	-3.226	-0.043
100	B058	-3.402	-3.512	0.110
100	B059	-3.345	-3.455	0.110
100	B060	-3.478	-3.417	-0.061
100	B061	-3.440	-3.283	-0.157
100	B062	-3.440	-3.359	-0.081
100	B063	-3.402	-3.341	-0.061
100	B064	-3.440	-3.474	0.034
	Max	-3.212	-3.154	0.300
	Average	-3.401	-3.385	-0.016
	Min	-3.535	-3.512	-0.214
	Std Dev	0.086	0.089	0.109

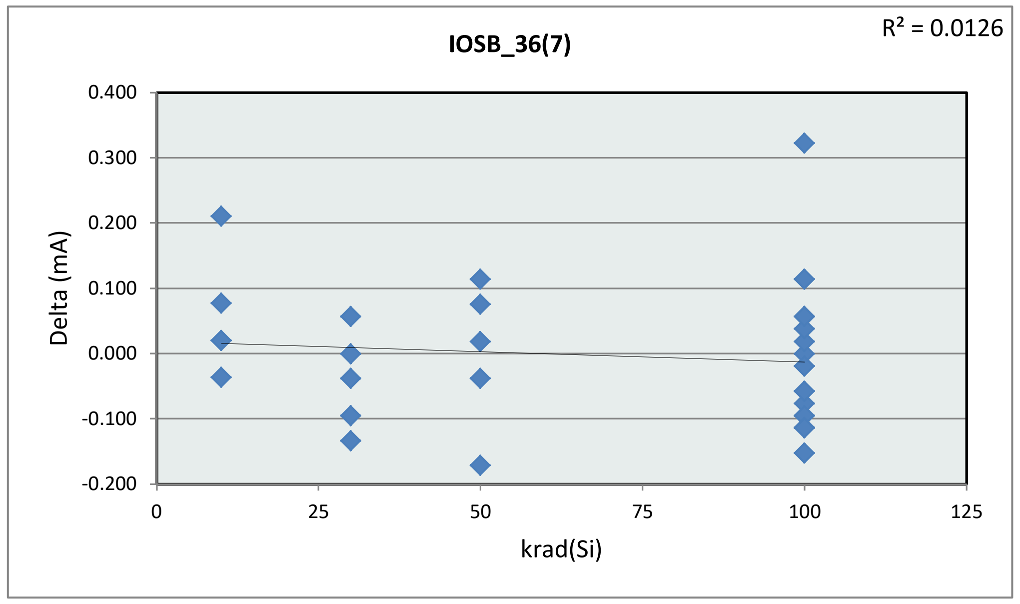


	IOSB_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.440	-3.512	-3.493	-3.512
Average	-3.322	-3.413	-3.428	-3.383
Max	-3.154	-3.302	-3.341	-3.226
UL	8.000	8.000	8.000	8.000

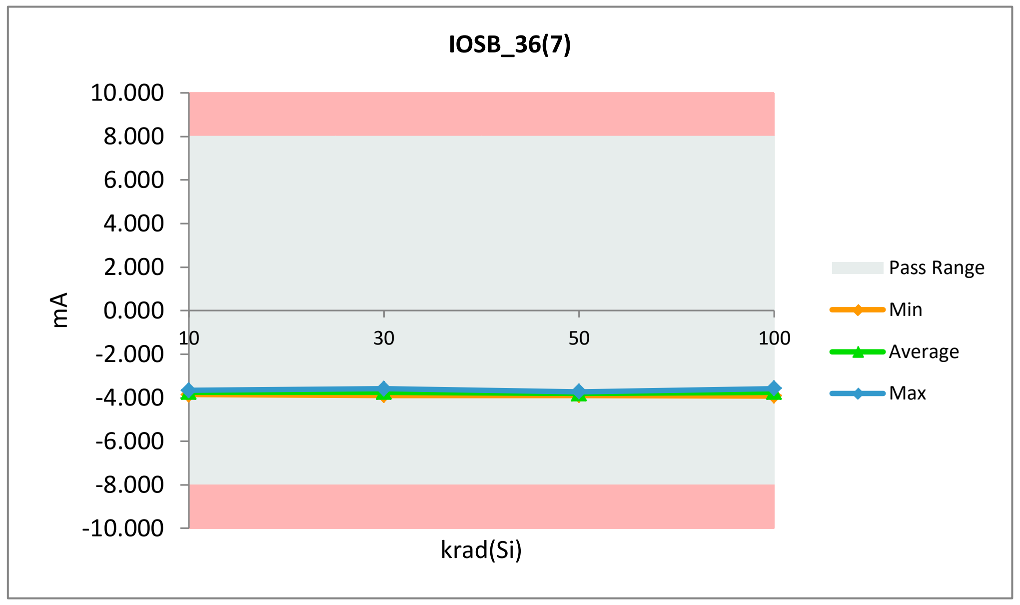


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-3.642	-3.852	0.210
10	7	-3.718	-3.681	-0.037
10	8	-3.585	-3.662	0.077
10	9	-3.680	-3.700	0.020
10	10	-3.794	-3.814	0.020
30	6	-3.727	-3.726	-0.001
30	7	-3.936	-3.897	-0.039
30	8	-3.689	-3.593	-0.096
30	9	-3.822	-3.688	-0.134
30	10	-3.765	-3.821	0.056
50	16	-3.841	-3.802	-0.039
50	17	-3.898	-3.726	-0.172
50	18	-3.765	-3.840	0.075
50	19	-3.784	-3.897	0.113
50	20	-3.746	-3.764	0.018
100	B043	-3.784	-3.631	-0.153
100	B044	-3.727	-3.783	0.056
100	B045	-3.670	-3.669	-0.001
100	B046	-3.860	-3.764	-0.096
100	B047	-3.765	-3.745	-0.020
100	B048	-3.765	-3.669	-0.096
100	B049	-3.898	-3.878	-0.020
100	B050	-3.822	-3.840	0.018
100	B051	-3.841	-3.764	-0.077
100	B052	-3.708	-3.764	0.056
100	B053	-3.594	-3.916	0.322
100	B054	-3.860	-3.802	-0.058
100	B055	-3.784	-3.840	0.056
100	B056	-3.689	-3.726	0.037
100	B057	-3.670	-3.574	-0.096
100	B058	-3.727	-3.840	0.113
100	B059	-3.689	-3.802	0.113
100	B060	-3.765	-3.707	-0.058
100	B061	-3.822	-3.669	-0.153
100	B062	-3.879	-3.765	-0.114
100	B063	-3.784	-3.669	-0.115
100	B064	-3.708	-3.764	0.056
	Max	-3.585	-3.574	0.322
	Average	-3.762	-3.758	-0.004
	Min	-3.936	-3.916	-0.172
	Std Dev	0.084	0.086	0.104

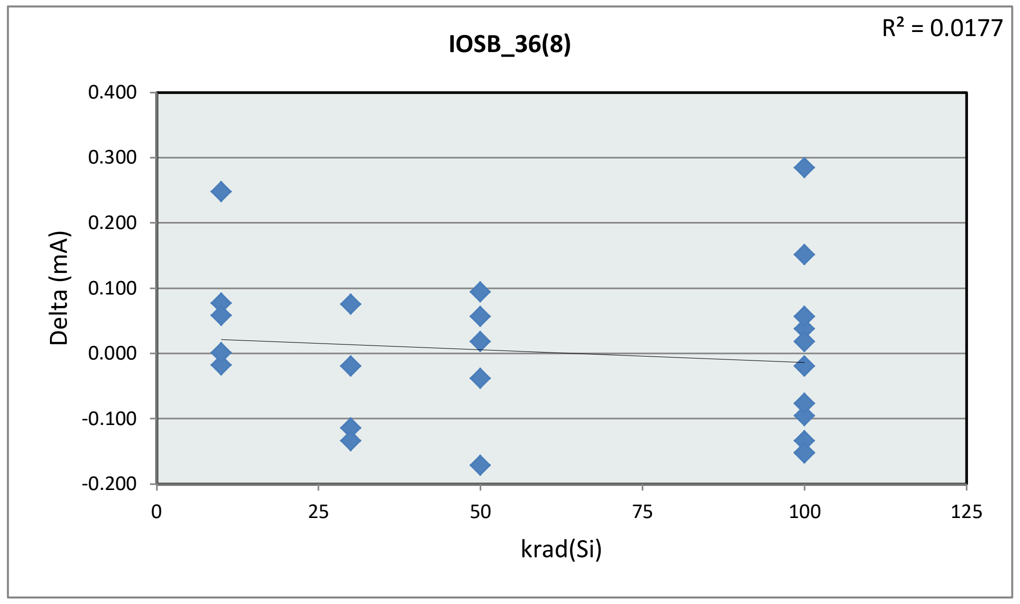


	IOSB_36(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.852	-3.897	-3.897	-3.916
Average	-3.742	-3.745	-3.806	-3.754
Max	-3.662	-3.593	-3.726	-3.574
UL	8.000	8.000	8.000	8.000

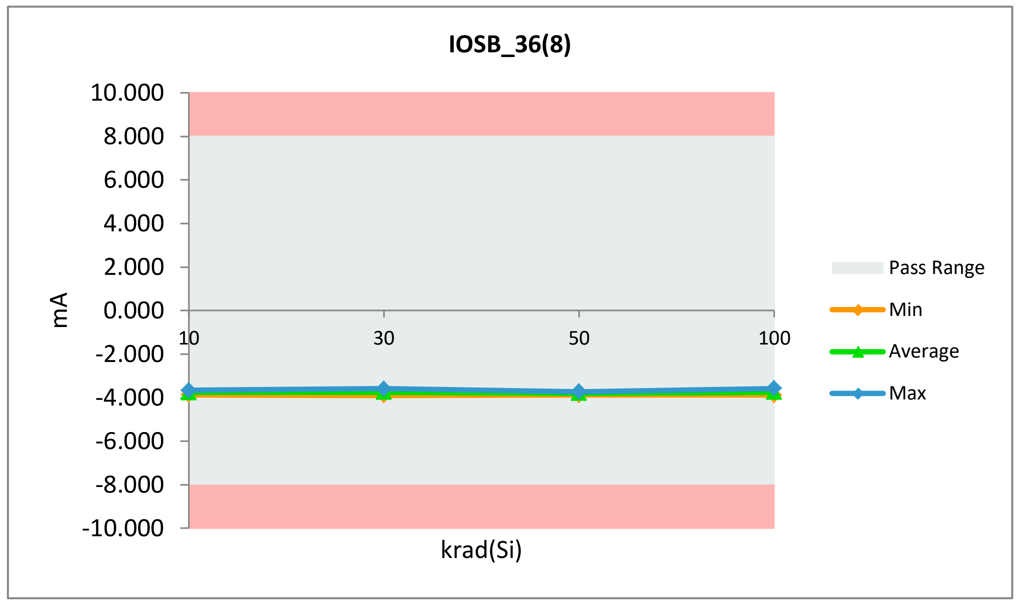


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-3.623	-3.871	0.248
10	7	-3.737	-3.719	-0.018
10	8	-3.585	-3.662	0.077
10	9	-3.699	-3.700	0.001
10	10	-3.775	-3.833	0.058
30	6	-3.727	-3.707	-0.020
30	7	-3.917	-3.897	-0.020
30	8	-3.708	-3.593	-0.115
30	9	-3.841	-3.707	-0.134
30	10	-3.746	-3.821	0.075
50	16	-3.841	-3.802	-0.039
50	17	-3.898	-3.726	-0.172
50	18	-3.765	-3.821	0.056
50	19	-3.784	-3.878	0.094
50	20	-3.746	-3.764	0.018
100	B043	-3.765	-3.631	-0.134
100	B044	-3.727	-3.764	0.037
100	B045	-3.670	-3.688	0.018
100	B046	-3.841	-3.764	-0.077
100	B047	-3.765	-3.745	-0.020
100	B048	-3.765	-3.669	-0.096
100	B049	-3.898	-3.878	-0.020
100	B050	-3.822	-3.840	0.018
100	B051	-3.841	-3.764	-0.077
100	B052	-3.708	-3.764	0.056
100	B053	-3.594	-3.878	0.284
100	B054	-3.841	-3.821	-0.020
100	B055	-3.784	-3.840	0.056
100	B056	-3.689	-3.707	0.018
100	B057	-3.651	-3.574	-0.077
100	B058	-3.708	-3.859	0.151
100	B059	-3.670	-3.821	0.151
100	B060	-3.765	-3.688	-0.077
100	B061	-3.822	-3.669	-0.153
100	B062	-3.898	-3.746	-0.152
100	B063	-3.822	-3.669	-0.153
100	B064	-3.708	-3.764	0.056
	Max	-3.585	-3.574	0.284
	Average	-3.760	-3.758	-0.003
	Min	-3.917	-3.897	-0.172
	Std Dev	0.084	0.084	0.107

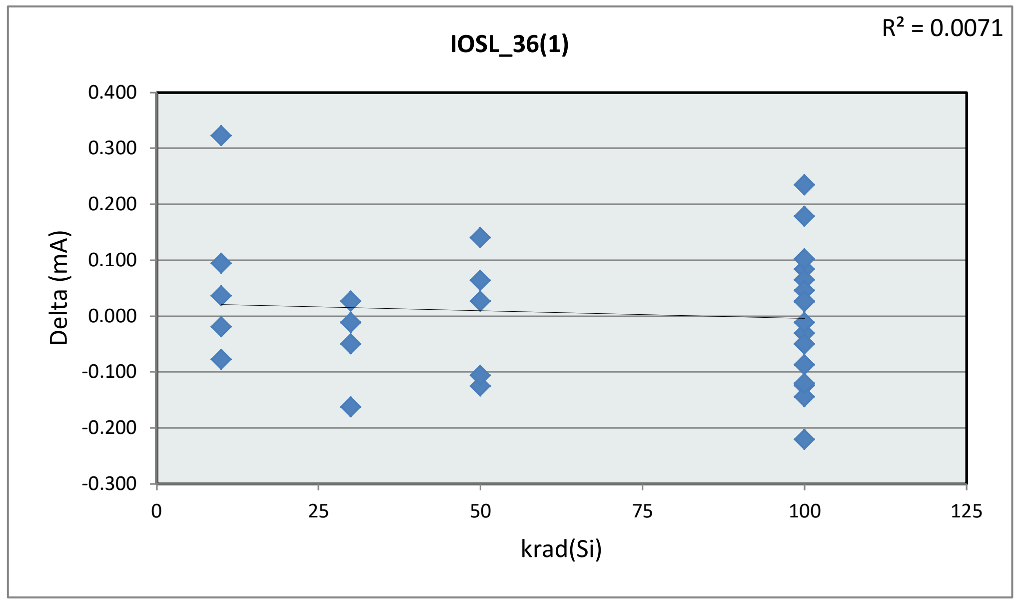


	IOSB_36(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.871	-3.897	-3.878	-3.878
Average	-3.757	-3.745	-3.798	-3.752
Max	-3.662	-3.593	-3.726	-3.574
UL	8.000	8.000	8.000	8.000

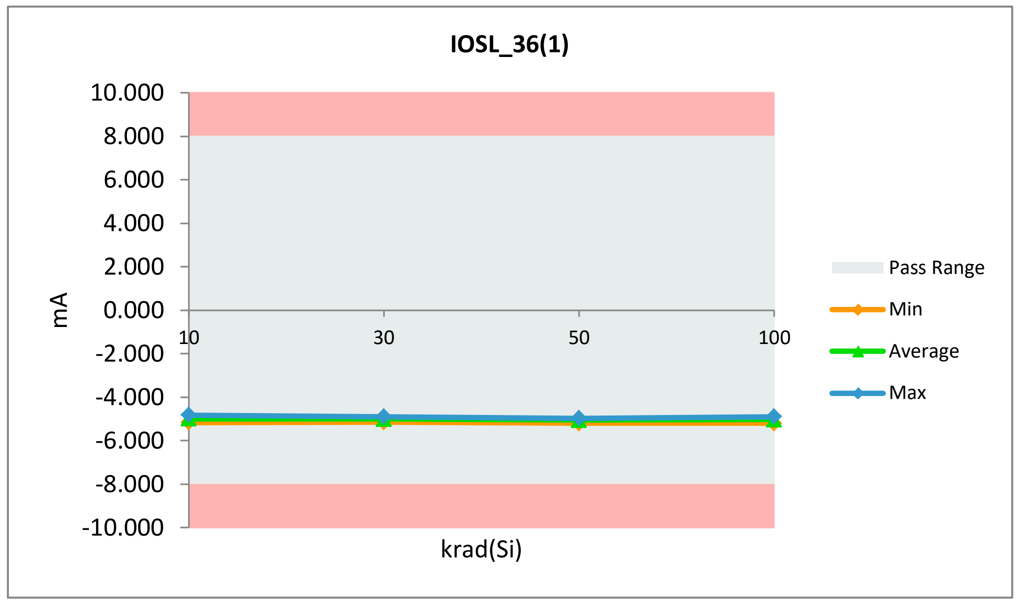


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-4.841	-5.163	0.322
10	7	-4.974	-5.068	0.094
10	8	-4.822	-4.858	0.036
10	9	-4.898	-4.820	-0.078
10	10	-5.069	-5.049	-0.020
30	6	-4.883	-4.910	0.027
30	7	-5.168	-5.156	-0.012
30	8	-5.054	-4.891	-0.163
30	9	-5.073	-5.023	-0.050
30	10	-5.073	-5.061	-0.012
50	16	-5.111	-4.985	-0.126
50	17	-5.073	-4.966	-0.107
50	18	-4.959	-5.099	0.140
50	19	-5.168	-5.194	0.026
50	20	-4.940	-5.004	0.064
100	B043	-5.168	-4.947	-0.221
100	B044	-4.921	-5.023	0.102
100	B045	-4.921	-4.947	0.026
100	B046	-5.054	-5.137	0.083
100	B047	-5.054	-4.929	-0.125
100	B048	-5.054	-4.929	-0.125
100	B049	-5.111	-5.175	0.064
100	B050	-5.092	-5.042	-0.050
100	B051	-5.092	-5.042	-0.050
100	B052	-4.883	-5.061	0.178
100	B053	-4.883	-5.118	0.235
100	B054	-5.168	-5.080	-0.088
100	B055	-5.054	-5.099	0.045
100	B056	-4.978	-4.891	-0.087
100	B057	-4.902	-4.929	0.027
100	B058	-4.959	-5.194	0.235
100	B059	-4.997	-5.099	0.102
100	B060	-5.035	-5.004	-0.031
100	B061	-5.092	-4.947	-0.145
100	B062	-5.149	-5.028	-0.121
100	B063	-5.073	-5.023	-0.050
100	B064	-5.035	-5.023	-0.012
	Max	-4.822	-4.820	0.322
	Average	-5.021	-5.025	0.004
	Min	-5.168	-5.194	-0.221
	Std Dev	0.098	0.096	0.120

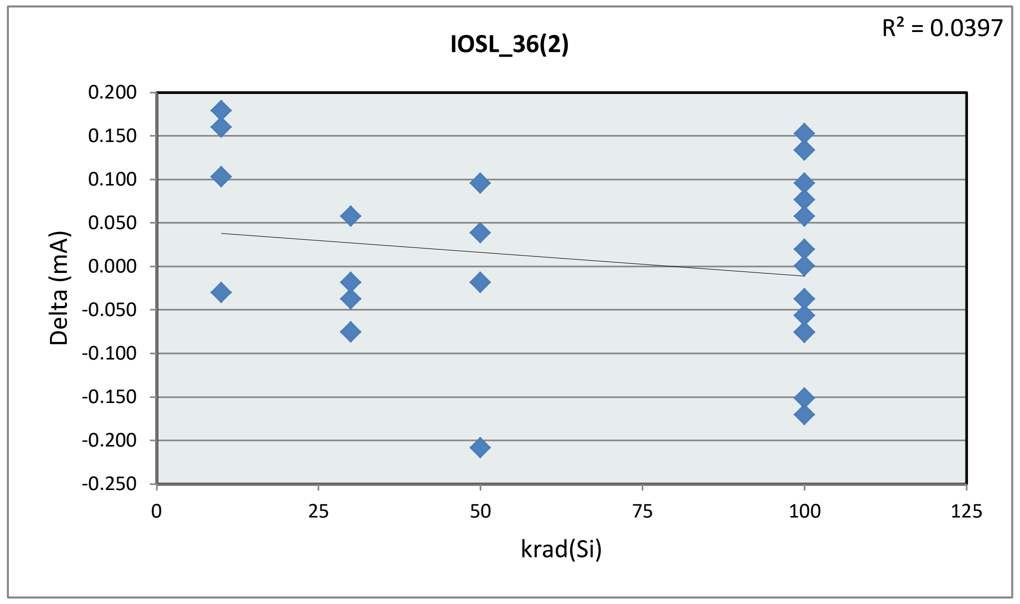


	IOSL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.163	-5.156	-5.194	-5.194
Average	-4.992	-5.008	-5.050	-5.030
Max	-4.820	-4.891	-4.966	-4.891
UL	8.000	8.000	8.000	8.000

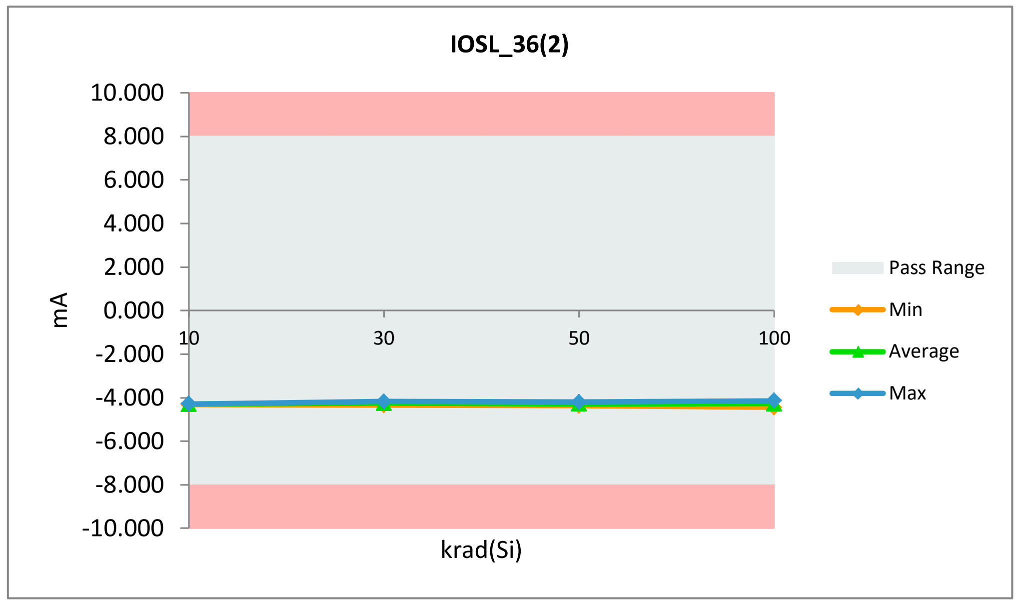


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-4.122	-4.301	0.179
10	7	-4.217	-4.320	0.103
10	8	-4.179	-4.282	0.103
10	9	-4.160	-4.320	0.160
10	10	-4.331	-4.301	-0.030
30	6	-4.180	-4.238	0.058
30	7	-4.427	-4.352	-0.075
30	8	-4.256	-4.181	-0.075
30	9	-4.275	-4.238	-0.037
30	10	-4.275	-4.257	-0.018
50	16	-4.332	-4.371	0.039
50	17	-4.408	-4.200	-0.208
50	18	-4.218	-4.314	0.096
50	19	-4.370	-4.352	-0.018
50	20	-4.218	-4.200	-0.018
100	B043	-4.389	-4.238	-0.151
100	B044	-4.199	-4.295	0.096
100	B045	-4.180	-4.143	-0.037
100	B046	-4.180	-4.314	0.134
100	B047	-4.313	-4.238	-0.075
100	B048	-4.237	-4.200	-0.037
100	B049	-4.313	-4.447	0.134
100	B050	-4.351	-4.181	-0.170
100	B051	-4.275	-4.295	0.020
100	B052	-4.161	-4.295	0.134
100	B053	-4.237	-4.314	0.077
100	B054	-4.408	-4.352	-0.056
100	B055	-4.218	-4.295	0.077
100	B056	-4.237	-4.181	-0.056
100	B057	-4.180	-4.238	0.058
100	B058	-4.256	-4.409	0.153
100	B059	-4.275	-4.276	0.001
100	B060	-4.332	-4.257	-0.075
100	B061	-4.389	-4.238	-0.151
100	B062	-4.408	-4.332	-0.076
100	B063	-4.294	-4.238	-0.056
100	B064	-4.427	-4.390	-0.037
	Max	-4.122	-4.143	0.179
	Average	-4.277	-4.281	0.004
	Min	-4.427	-4.447	-0.208
	Std Dev	0.087	0.069	0.100

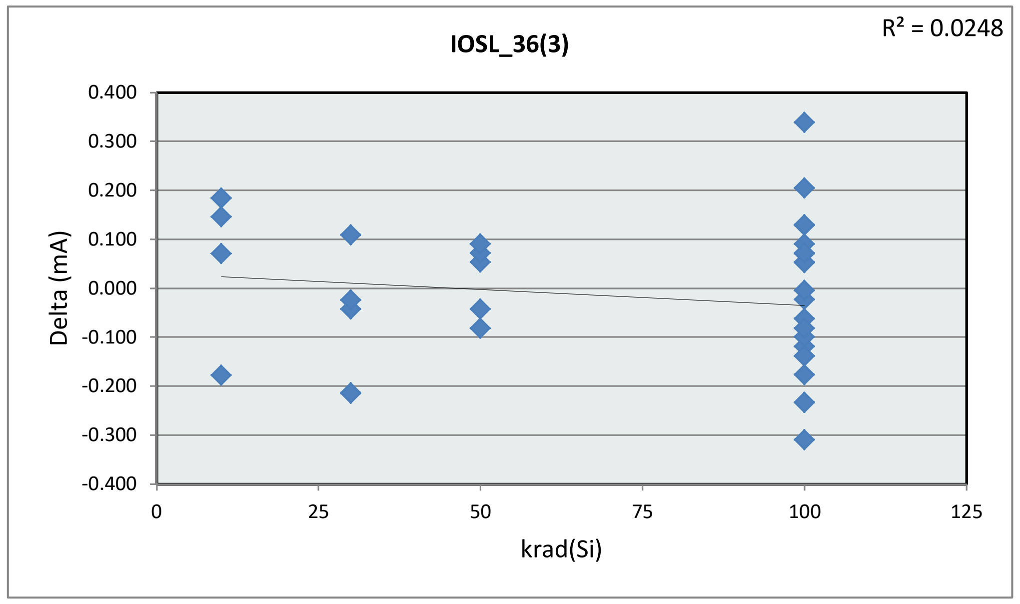


	IOSL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.320	-4.352	-4.371	-4.447
Average	-4.305	-4.253	-4.287	-4.280
Max	-4.282	-4.181	-4.200	-4.143
UL	8.000	8.000	8.000	8.000

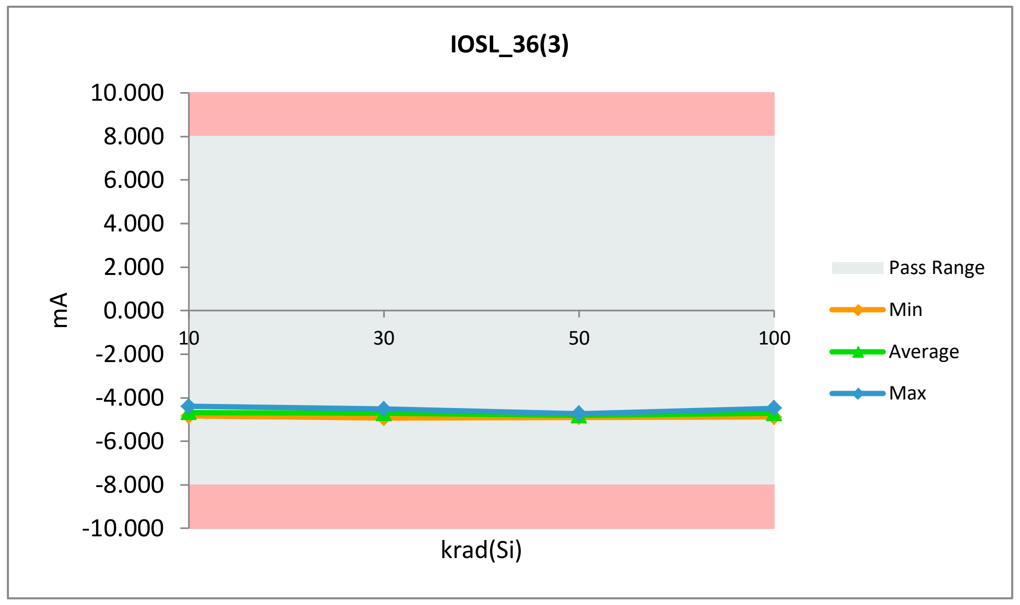


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-4.572	-4.394	-0.178
10	7	-4.610	-4.680	0.070
10	8	-4.534	-4.680	0.146
10	9	-4.629	-4.813	0.184
10	10	-4.648	-4.832	0.184
30	6	-4.735	-4.692	-0.043
30	7	-4.964	-4.940	-0.024
30	8	-4.735	-4.521	-0.214
30	9	-4.850	-4.635	-0.215
30	10	-4.678	-4.787	0.109
50	16	-4.907	-4.864	-0.043
50	17	-4.812	-4.730	-0.082
50	18	-4.773	-4.826	0.053
50	19	-4.831	-4.902	0.071
50	20	-4.640	-4.730	0.090
100	B043	-4.735	-4.502	-0.233
100	B044	-4.793	-4.673	-0.120
100	B045	-4.545	-4.635	0.090
100	B046	-4.888	-4.749	-0.139
100	B047	-4.659	-4.730	0.071
100	B048	-4.773	-4.540	-0.233
100	B049	-4.907	-4.883	-0.024
100	B050	-4.850	-4.845	-0.005
100	B051	-4.926	-4.616	-0.310
100	B052	-4.754	-4.807	0.053
100	B053	-4.526	-4.864	0.338
100	B054	-4.850	-4.787	-0.063
100	B055	-4.754	-4.883	0.129
100	B056	-4.659	-4.711	0.052
100	B057	-4.583	-4.483	-0.100
100	B058	-4.659	-4.864	0.205
100	B059	-4.697	-4.826	0.129
100	B060	-4.869	-4.787	-0.082
100	B061	-4.793	-4.616	-0.177
100	B062	-4.812	-4.578	-0.234
100	B063	-4.773	-4.635	-0.138
100	B064	-4.735	-4.807	0.072
	Max	-4.526	-4.394	0.338
	Average	-4.742	-4.726	-0.017
	Min	-4.964	-4.940	-0.310
	Std Dev	0.117	0.133	0.151

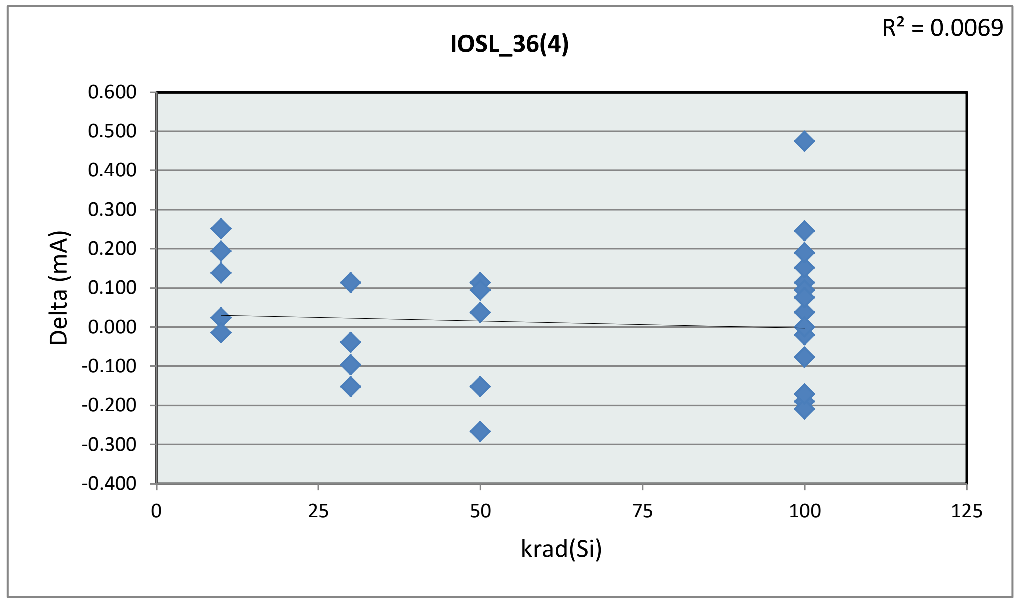


	IOSL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.832	-4.940	-4.902	-4.883
Average	-4.680	-4.715	-4.810	-4.719
Max	-4.394	-4.521	-4.730	-4.483
UL	8.000	8.000	8.000	8.000

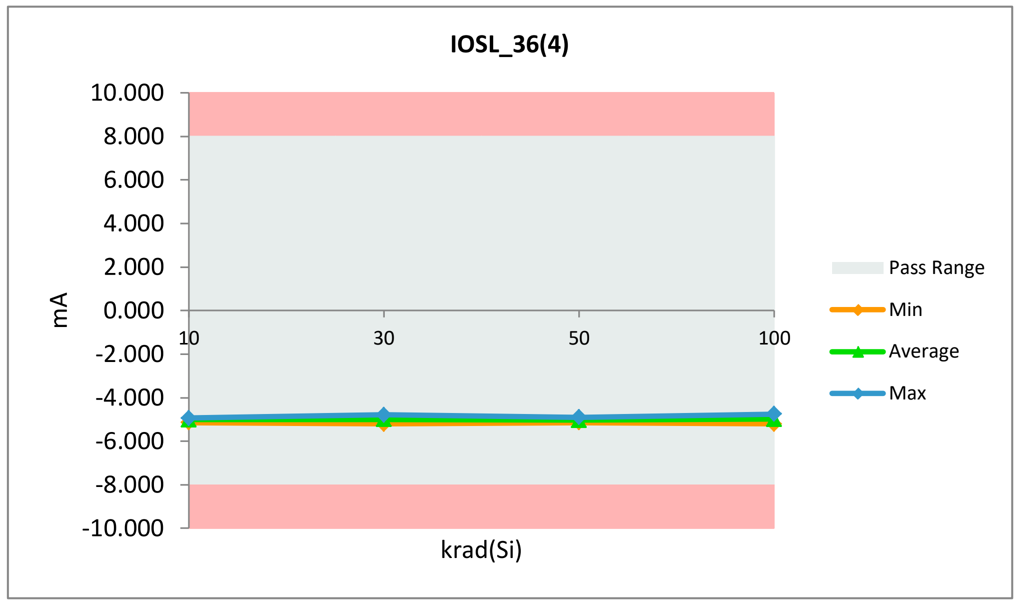


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-4.876	-5.070	0.194
10	7	-4.914	-4.937	0.023
10	8	-4.686	-4.937	0.251
10	9	-4.990	-4.975	-0.015
10	10	-5.009	-5.146	0.137
30	6	-5.075	-4.979	-0.096
30	7	-5.246	-5.207	-0.039
30	8	-4.885	-4.789	-0.096
30	9	-5.075	-4.922	-0.153
30	10	-4.961	-5.074	0.113
50	16	-5.208	-5.055	-0.153
50	17	-5.170	-4.903	-0.267
50	18	-4.961	-5.074	0.113
50	19	-5.056	-5.150	0.094
50	20	-4.942	-4.979	0.037
100	B043	-4.999	-4.808	-0.191
100	B044	-4.961	-4.960	-0.001
100	B045	-4.733	-4.846	0.113
100	B046	-5.056	-5.036	-0.020
100	B047	-4.942	-4.979	0.037
100	B048	-4.980	-4.808	-0.172
100	B049	-5.189	-5.112	-0.077
100	B050	-4.961	-5.055	0.094
100	B051	-5.113	-4.941	-0.172
100	B052	-4.942	-4.979	0.037
100	B053	-4.733	-5.207	0.474
100	B054	-5.151	-4.979	-0.172
100	B055	-5.037	-5.188	0.151
100	B056	-4.923	-4.998	0.075
100	B057	-4.828	-4.751	-0.077
100	B058	-4.923	-5.169	0.246
100	B059	-4.866	-5.055	0.189
100	B060	-5.018	-4.941	-0.077
100	B061	-5.056	-4.846	-0.210
100	B062	-5.132	-5.132	0.000
100	B063	-5.037	-4.865	-0.172
100	B064	-4.904	-4.979	0.075
	Max	-4.686	-4.751	0.474
	Average	-4.988	-4.995	0.008
	Min	-5.246	-5.207	-0.267
	Std Dev	0.129	0.121	0.157



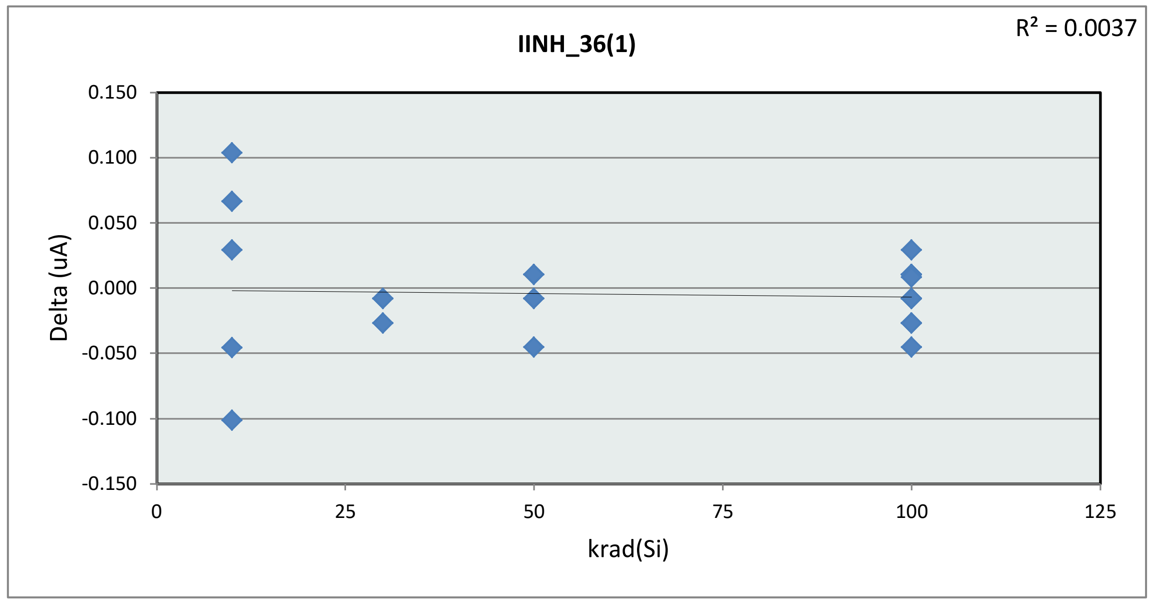
	IOSL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.146	-5.207	-5.150	-5.207
Average	-5.013	-4.994	-5.032	-4.983
Max	-4.937	-4.789	-4.903	-4.751
UL	8.000	8.000	8.000	8.000



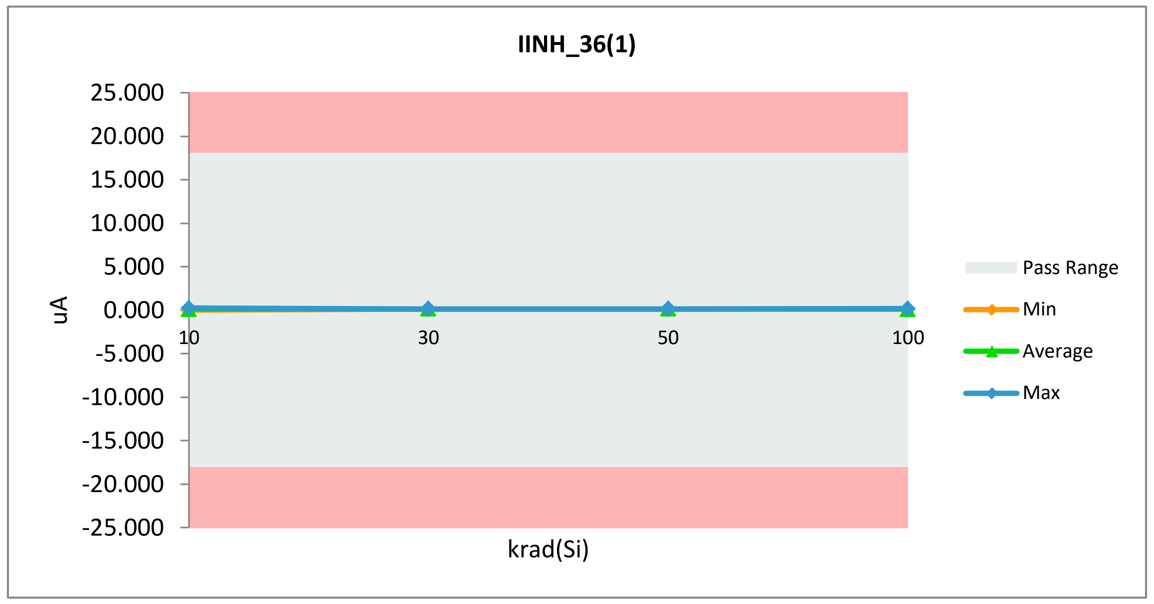
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	0.130	0.175	-0.046
10	7	0.148	0.045	0.103
10	8	0.148	0.082	0.066
10	9	0.130	0.101	0.029
10	10	0.148	0.250	-0.102
30	6	0.125	0.133	-0.008
30	7	0.125	0.133	-0.008
30	8	0.125	0.151	-0.027
30	9	0.125	0.151	-0.027
30	10	0.143	0.151	-0.008
50	16	0.143	0.133	0.010
50	17	0.143	0.151	-0.008
50	18	0.143	0.133	0.010
50	19	0.143	0.151	-0.008
50	20	0.106	0.151	-0.045
100	B043	0.143	0.189	-0.045
100	B044	0.125	0.151	-0.027
100	B045	0.125	0.151	-0.027
100	B046	0.125	0.151	-0.027
100	B047	0.125	0.133	-0.008
100	B048	0.125	0.133	-0.008
100	B049	0.125	0.151	-0.027
100	B050	0.143	0.133	0.010
100	B051	0.125	0.133	-0.008
100	B052	0.125	0.133	-0.008
100	B053	0.143	0.133	0.010
100	B054	0.143	0.151	-0.008
100	B055	0.125	0.114	0.010
100	B056	0.143	0.133	0.010
100	B057	0.125	0.133	-0.008
100	B058	0.143	0.133	0.010
100	B059	0.143	0.133	0.010
100	B060	0.106	0.133	-0.027
100	B061	0.125	0.114	0.010
100	B062	0.143	0.135	0.008
100	B063	0.125	0.133	-0.008
100	B064	0.143	0.114	0.029
	Max	0.148	0.250	0.103
	Average	0.133	0.138	-0.005
	Min	0.106	0.045	-0.102
	Std Dev	0.011	0.031	0.033



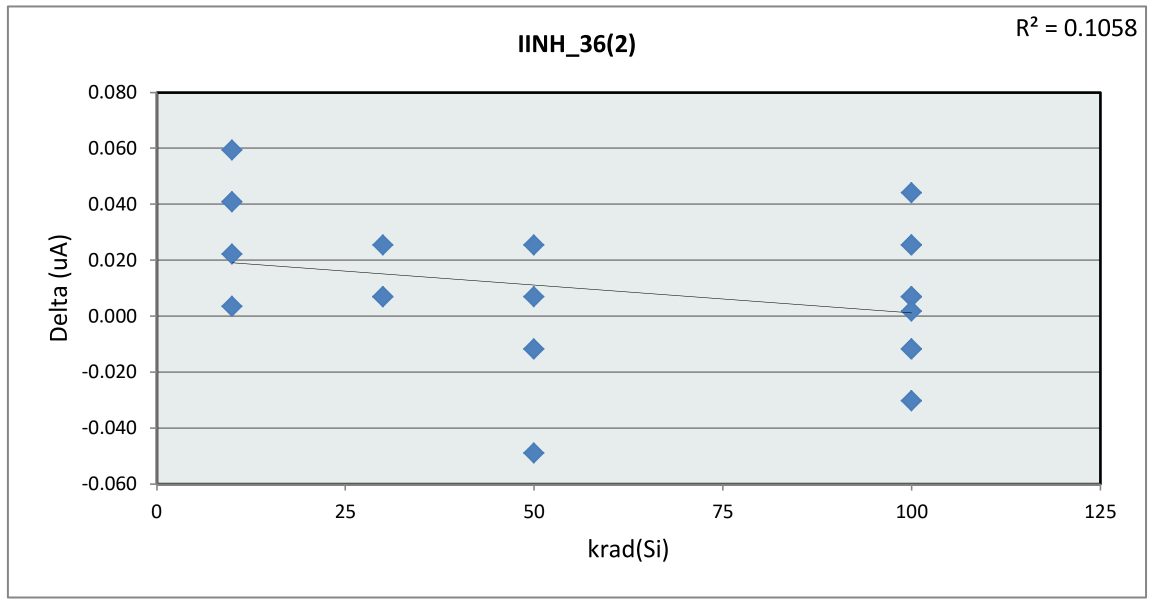
	IINH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.045	0.133	0.133	0.114
Average	0.130	0.144	0.144	0.137
Max	0.250	0.151	0.151	0.189
UL	18.000	18.000	18.000	18.000



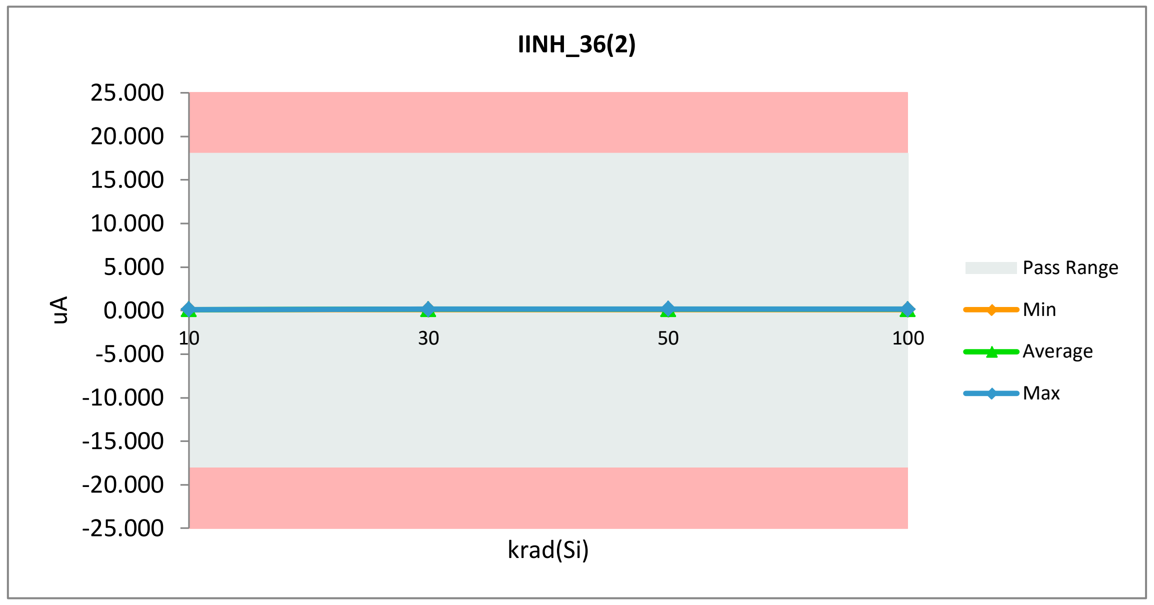
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.156	0.116	0.041
10	7	0.175	0.116	0.059
10	8	0.156	0.116	0.041
10	9	0.156	0.134	0.022
10	10	0.138	0.134	0.003
30	6	0.163	0.138	0.025
30	7	0.163	0.157	0.007
30	8	0.163	0.157	0.007
30	9	0.163	0.157	0.007
30	10	0.163	0.157	0.007
50	16	0.145	0.157	-0.012
50	17	0.163	0.157	0.007
50	18	0.163	0.138	0.025
50	19	0.145	0.157	-0.012
50	20	0.126	0.175	-0.049
100	B043	0.163	0.157	0.007
100	B044	0.163	0.138	0.025
100	B045	0.145	0.157	-0.012
100	B046	0.126	0.157	-0.030
100	B047	0.145	0.157	-0.012
100	B048	0.145	0.138	0.007
100	B049	0.145	0.157	-0.012
100	B050	0.163	0.119	0.044
100	B051	0.163	0.138	0.025
100	B052	0.145	0.138	0.007
100	B053	0.145	0.157	-0.012
100	B054	0.163	0.157	0.007
100	B055	0.145	0.157	-0.012
100	B056	0.145	0.138	0.007
100	B057	0.145	0.138	0.007
100	B058	0.145	0.157	-0.012
100	B059	0.163	0.138	0.025
100	B060	0.126	0.157	-0.030
100	B061	0.163	0.138	0.025
100	B062	0.145	0.143	0.002
100	B063	0.126	0.138	-0.012
100	B064	0.163	0.138	0.025
	Max	0.175	0.175	0.059
	Average	0.152	0.145	0.007
	Min	0.126	0.116	-0.049
	Std Dev	0.013	0.014	0.022

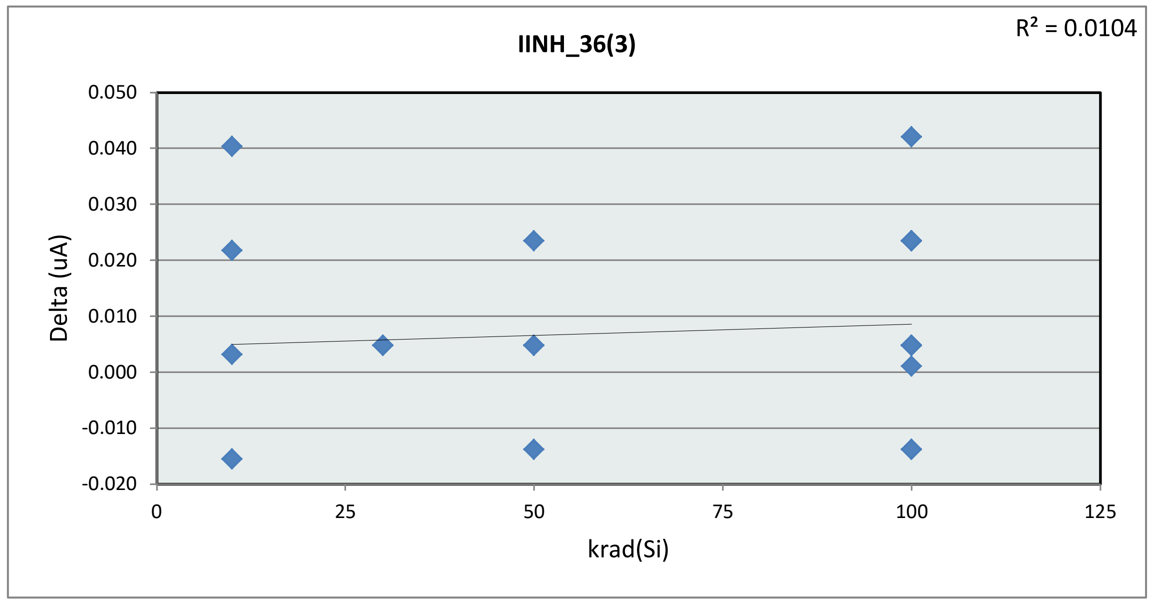


	IINH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.116	0.138	0.138	0.119
Average	0.123	0.153	0.157	0.146
Max	0.134	0.157	0.175	0.157
UL	18.000	18.000	18.000	18.000

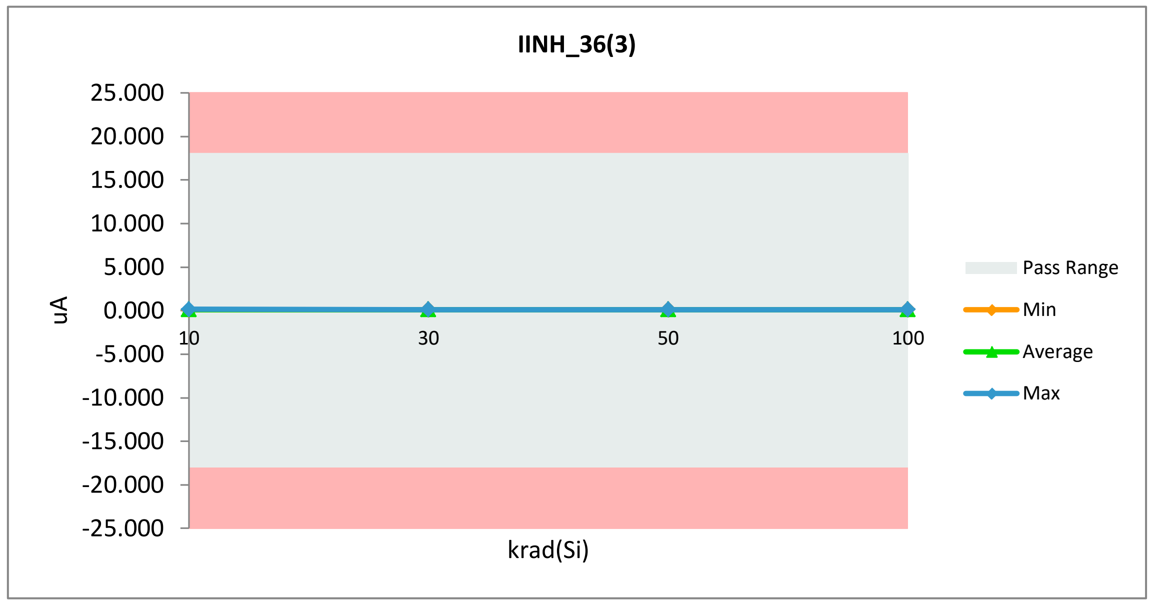


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.138	0.153	-0.016
10	7	0.157	0.153	0.003
10	8	0.138	0.116	0.022
10	9	0.138	0.098	0.040
10	10	0.138	0.153	-0.016
30	6	0.119	0.115	0.005
30	7	0.138	0.133	0.005
30	8	0.138	0.133	0.005
30	9	0.138	0.133	0.005
30	10	0.138	0.133	0.005
50	16	0.138	0.133	0.005
50	17	0.138	0.133	0.005
50	18	0.138	0.115	0.023
50	19	0.138	0.133	0.005
50	20	0.119	0.133	-0.014
100	B043	0.138	0.133	0.005
100	B044	0.138	0.133	0.005
100	B045	0.138	0.133	0.005
100	B046	0.119	0.133	-0.014
100	B047	0.138	0.133	0.005
100	B048	0.119	0.115	0.005
100	B049	0.138	0.133	0.005
100	B050	0.138	0.115	0.023
100	B051	0.138	0.115	0.023
100	B052	0.119	0.115	0.005
100	B053	0.138	0.115	0.023
100	B054	0.138	0.133	0.005
100	B055	0.119	0.115	0.005
100	B056	0.138	0.115	0.023
100	B057	0.119	0.133	-0.014
100	B058	0.138	0.133	0.005
100	B059	0.138	0.115	0.023
100	B060	0.119	0.133	-0.014
100	B061	0.138	0.115	0.023
100	B062	0.138	0.137	0.001
100	B063	0.138	0.133	0.005
100	B064	0.157	0.115	0.042
	Max	0.157	0.153	0.042
	Average	0.135	0.128	0.007
	Min	0.119	0.098	-0.016
	Std Dev	0.009	0.013	0.014

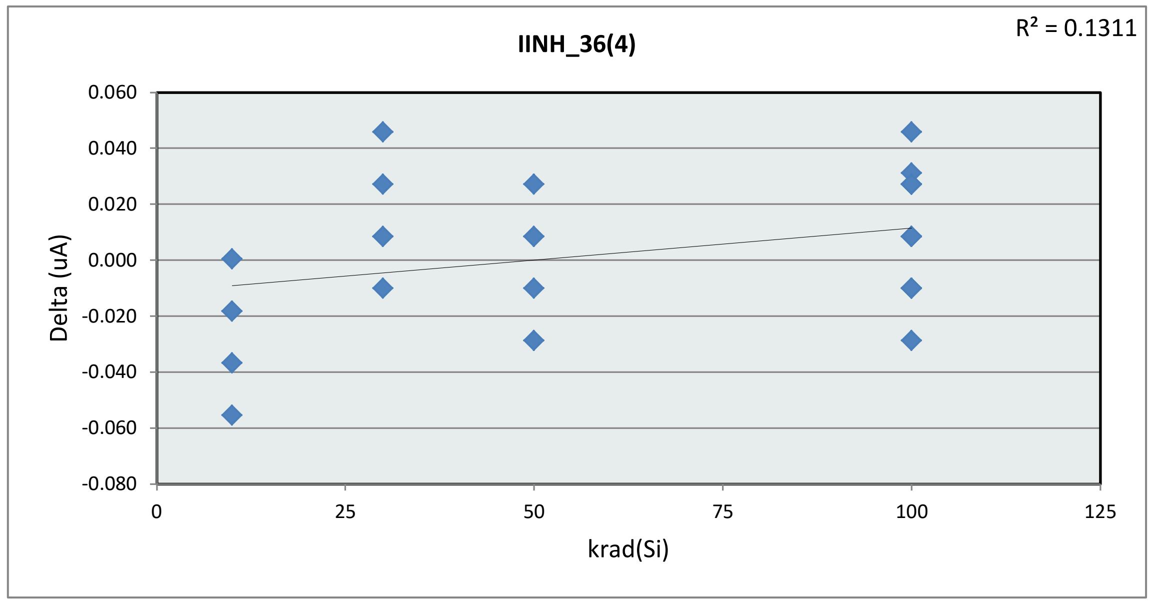


	IINH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.098	0.115	0.115	0.115
Average	0.135	0.130	0.130	0.125
Max	0.153	0.133	0.133	0.137
UL	18.000	18.000	18.000	18.000

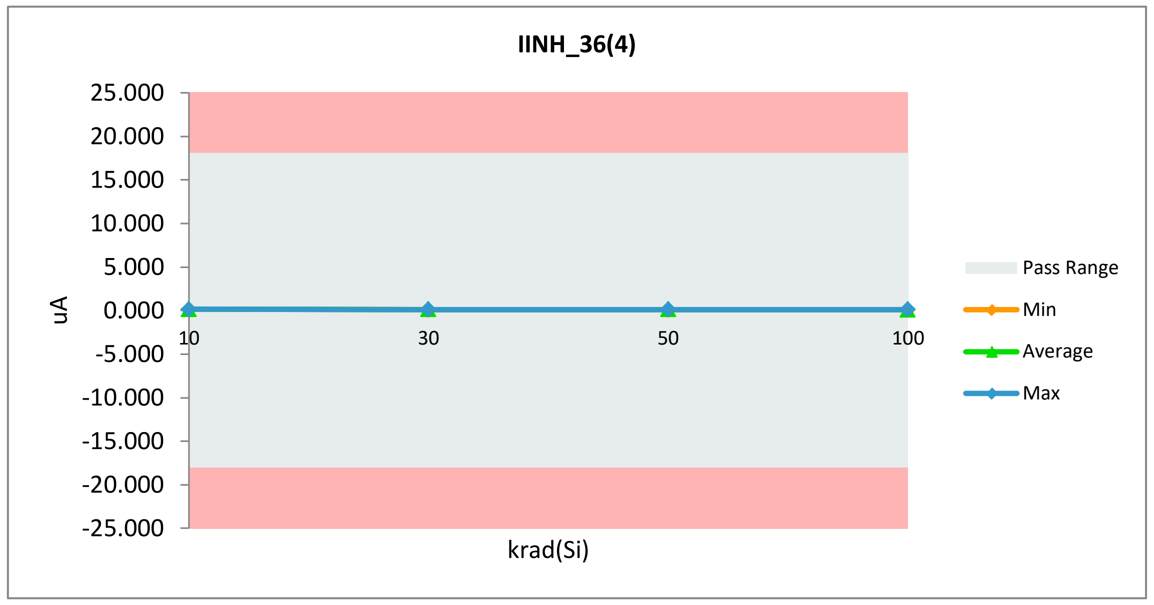


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	0.122	0.140	-0.018
10	7	0.141	0.140	0.000
10	8	0.122	0.140	-0.018
10	9	0.122	0.159	-0.037
10	10	0.104	0.159	-0.055
30	6	0.145	0.118	0.027
30	7	0.126	0.118	0.009
30	8	0.126	0.118	0.009
30	9	0.108	0.118	-0.010
30	10	0.145	0.099	0.046
50	16	0.126	0.118	0.009
50	17	0.126	0.118	0.009
50	18	0.126	0.099	0.027
50	19	0.108	0.118	-0.010
50	20	0.089	0.118	-0.029
100	B043	0.126	0.118	0.009
100	B044	0.126	0.118	0.009
100	B045	0.108	0.118	-0.010
100	B046	0.108	0.118	-0.010
100	B047	0.108	0.118	-0.010
100	B048	0.108	0.099	0.009
100	B049	0.126	0.099	0.027
100	B050	0.126	0.099	0.027
100	B051	0.126	0.099	0.027
100	B052	0.108	0.099	0.009
100	B053	0.108	0.118	-0.010
100	B054	0.126	0.118	0.009
100	B055	0.108	0.118	-0.010
100	B056	0.126	0.099	0.027
100	B057	0.108	0.099	0.009
100	B058	0.108	0.118	-0.010
100	B059	0.126	0.099	0.027
100	B060	0.089	0.118	-0.029
100	B061	0.126	0.099	0.027
100	B062	0.126	0.095	0.031
100	B063	0.145	0.118	0.027
100	B064	0.126	0.081	0.046
	Max	0.145	0.159	0.046
	Average	0.120	0.115	0.005
	Min	0.089	0.081	-0.055
	Std Dev	0.014	0.017	0.023



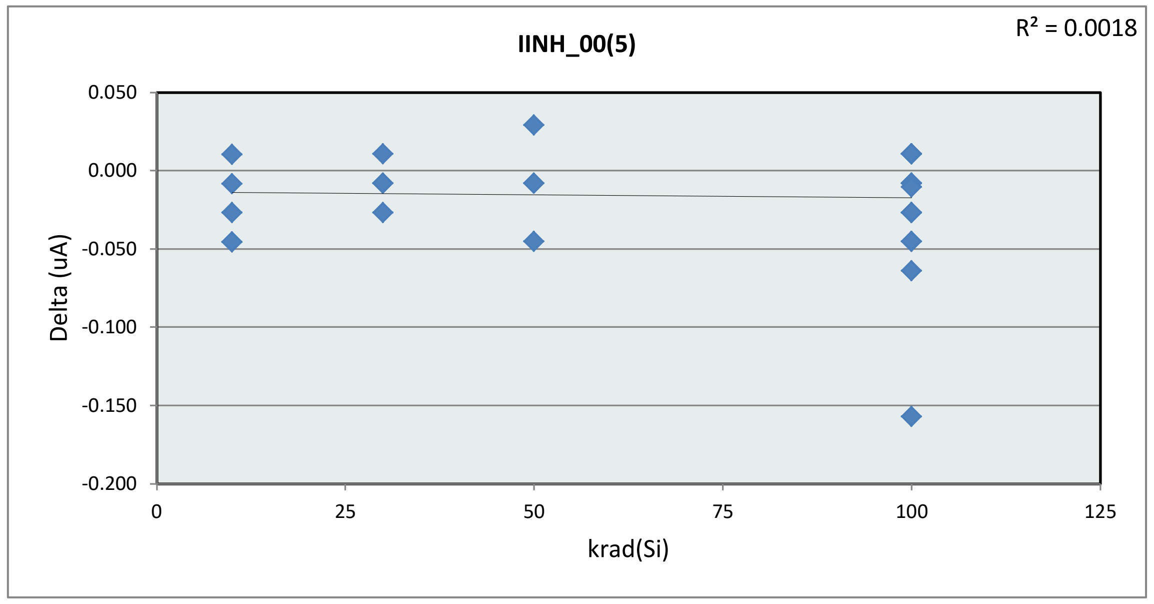
	IINH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.140	0.099	0.099	0.081
Average	0.148	0.114	0.114	0.108
Max	0.159	0.118	0.118	0.118
UL	18.000	18.000	18.000	18.000



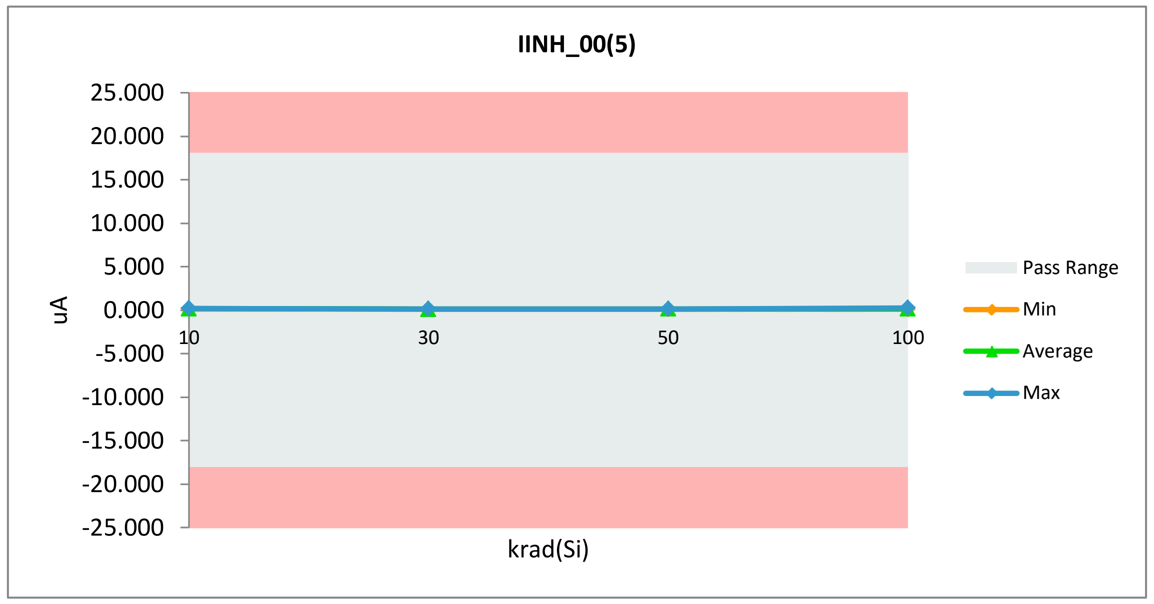
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_00(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.148	0.175	-0.027
10	7	0.167	0.212	-0.046
10	8	0.148	0.156	-0.008
10	9	0.130	0.175	-0.046
10	10	0.167	0.156	0.010
30	6	0.106	0.114	-0.008
30	7	0.125	0.133	-0.008
30	8	0.143	0.151	-0.008
30	9	0.125	0.151	-0.027
30	10	0.143	0.133	0.010
50	16	0.125	0.133	-0.008
50	17	0.143	0.151	-0.008
50	18	0.143	0.114	0.029
50	19	0.143	0.151	-0.008
50	20	0.106	0.151	-0.045
100	B043	0.125	0.282	-0.157
100	B044	0.125	0.151	-0.027
100	B045	0.106	0.151	-0.045
100	B046	0.125	0.133	-0.008
100	B047	0.106	0.133	-0.027
100	B048	0.106	0.133	-0.027
100	B049	0.125	0.133	-0.008
100	B050	0.143	0.133	0.010
100	B051	0.125	0.133	-0.008
100	B052	0.125	0.114	0.010
100	B053	0.143	0.133	0.010
100	B054	0.125	0.133	-0.008
100	B055	0.125	0.114	0.010
100	B056	0.125	0.114	0.010
100	B057	0.106	0.133	-0.027
100	B058	0.125	0.133	-0.008
100	B059	0.143	0.133	0.010
100	B060	0.087	0.151	-0.064
100	B061	0.125	0.133	-0.008
100	B062	0.143	0.154	-0.010
100	B063	0.106	0.151	-0.045
100	B064	0.125	0.114	0.010
	Max	0.167	0.282	0.029
	Average	0.128	0.145	-0.016
	Min	0.087	0.114	-0.157
	Std Dev	0.018	0.031	0.032

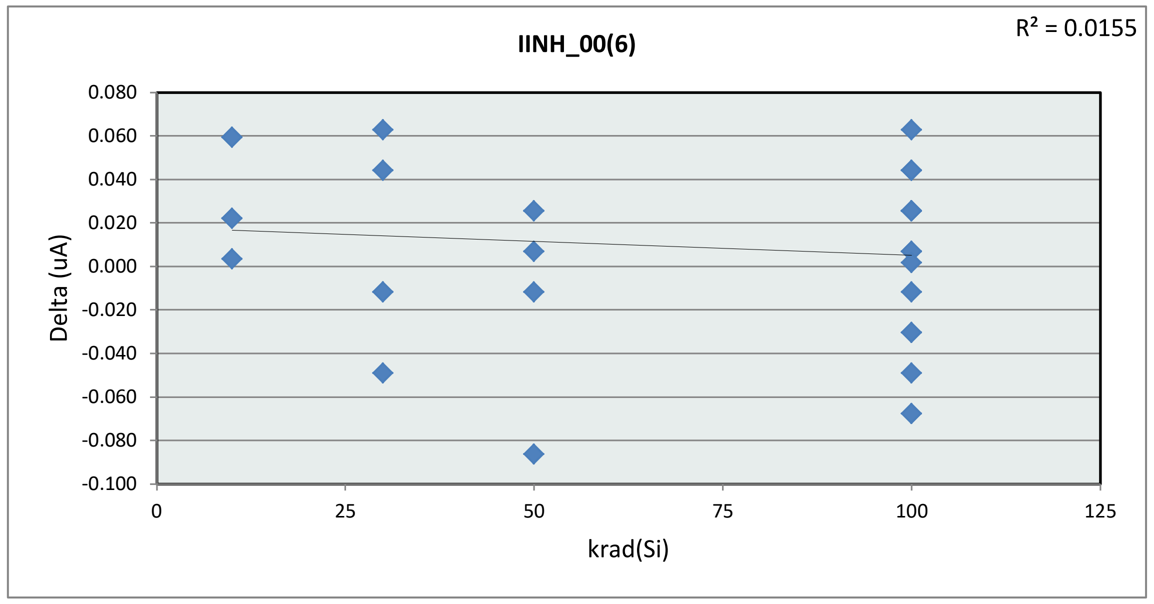


	IINH_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.156	0.114	0.114	0.114
Average	0.175	0.137	0.140	0.141
Max	0.212	0.151	0.151	0.282
UL	18.000	18.000	18.000	18.000

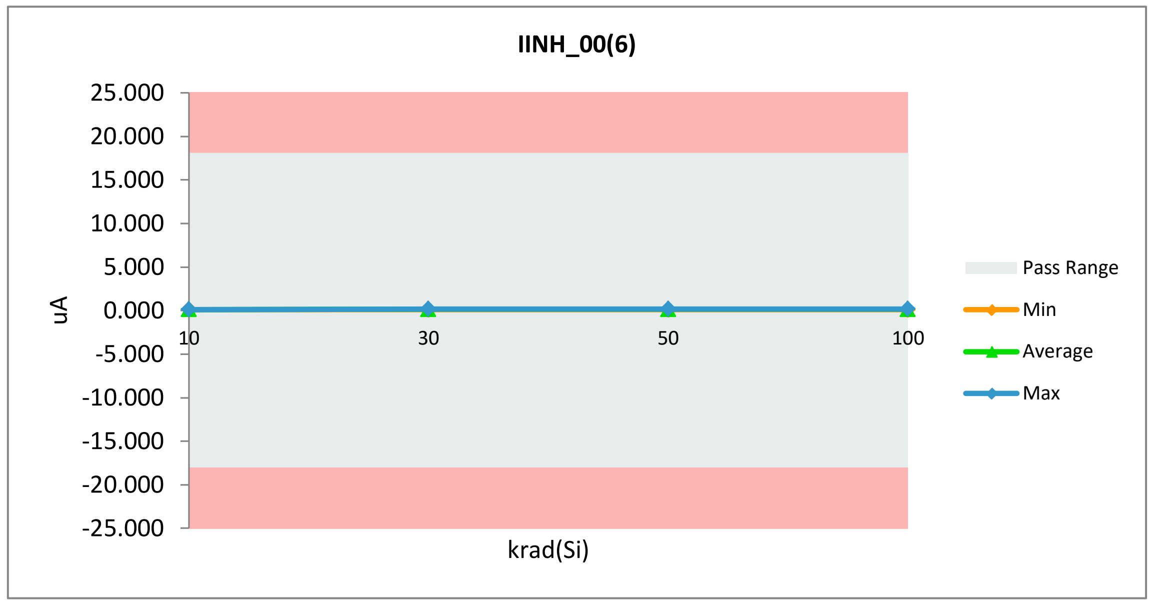


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_00(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.138	0.116	0.022
10	7	0.175	0.116	0.059
10	8	0.138	0.116	0.022
10	9	0.175	0.116	0.059
10	10	0.119	0.116	0.004
30	6	0.163	0.119	0.044
30	7	0.145	0.157	-0.012
30	8	0.126	0.138	-0.012
30	9	0.126	0.175	-0.049
30	10	0.182	0.119	0.063
50	16	0.126	0.138	-0.012
50	17	0.145	0.138	0.007
50	18	0.145	0.119	0.025
50	19	0.163	0.138	0.025
50	20	0.108	0.194	-0.086
100	B043	0.145	0.119	0.025
100	B044	0.126	0.194	-0.068
100	B045	0.182	0.138	0.044
100	B046	0.126	0.175	-0.049
100	B047	0.163	0.138	0.025
100	B048	0.163	0.138	0.025
100	B049	0.182	0.175	0.007
100	B050	0.145	0.101	0.044
100	B051	0.182	0.157	0.025
100	B052	0.126	0.101	0.025
100	B053	0.163	0.119	0.044
100	B054	0.145	0.175	-0.030
100	B055	0.126	0.119	0.007
100	B056	0.182	0.119	0.063
100	B057	0.108	0.175	-0.068
100	B058	0.163	0.175	-0.012
100	B059	0.126	0.157	-0.030
100	B060	0.145	0.138	0.007
100	B061	0.182	0.157	0.025
100	B062	0.145	0.143	0.002
100	B063	0.163	0.138	0.025
100	B064	0.182	0.157	0.025
	Max	0.182	0.194	0.063
	Average	0.150	0.141	0.009
	Min	0.108	0.101	-0.086
	Std Dev	0.023	0.026	0.038



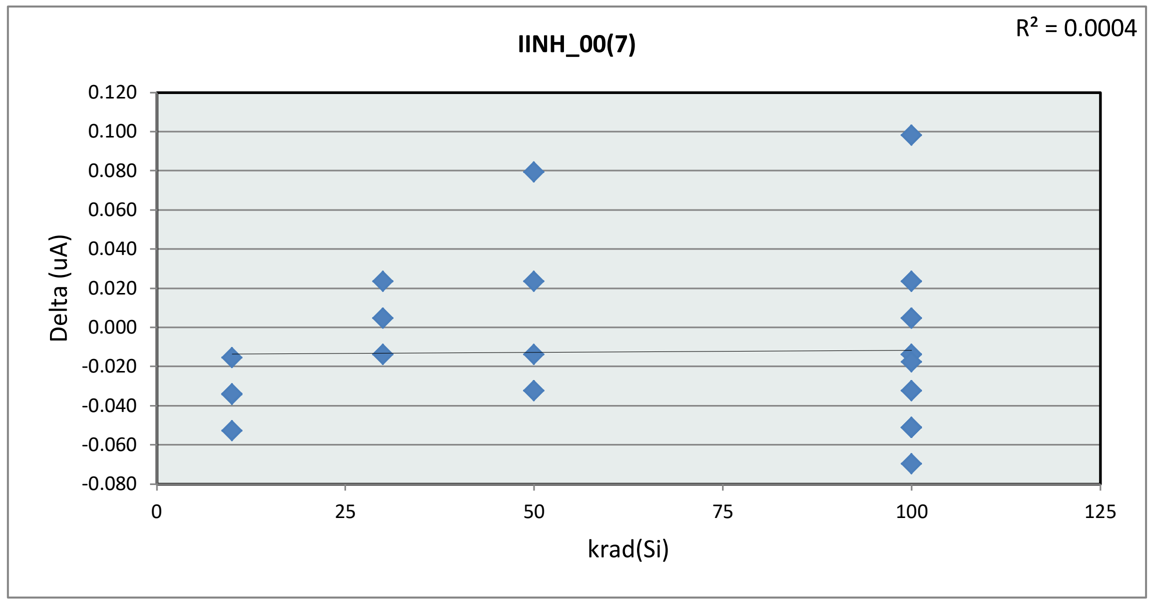
	IINH_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.116	0.119	0.119	0.101
Average	0.116	0.142	0.145	0.146
Max	0.116	0.175	0.194	0.194
UL	18.000	18.000	18.000	18.000



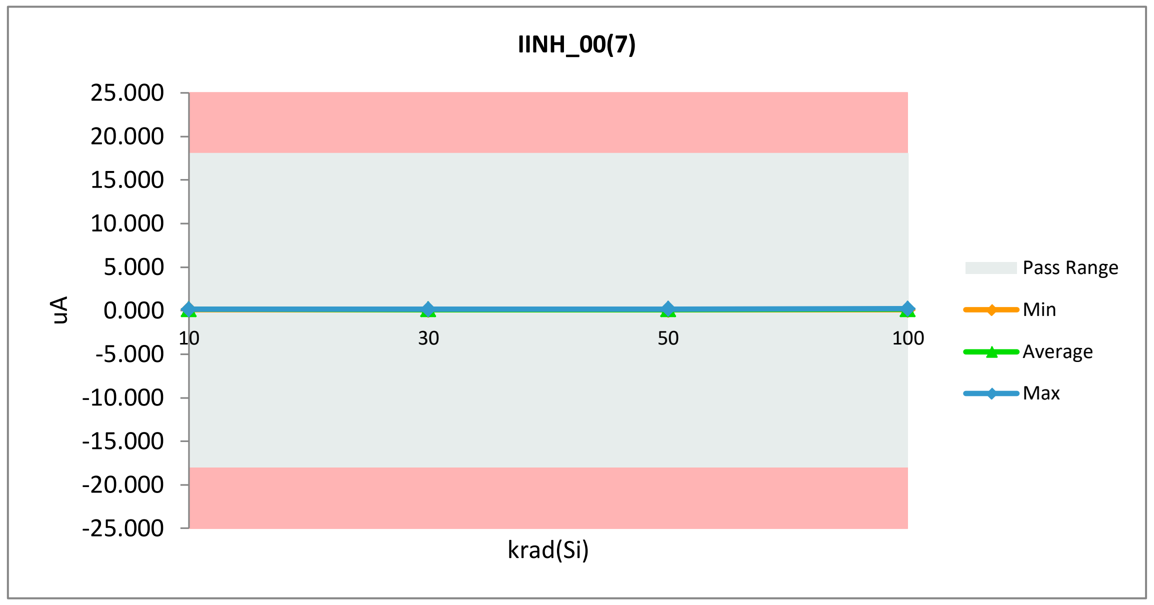
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_00(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	0.101	0.135	-0.034
10	7	0.119	0.153	-0.034
10	8	0.119	0.153	-0.034
10	9	0.101	0.153	-0.053
10	10	0.101	0.116	-0.016
30	6	0.101	0.096	0.005
30	7	0.101	0.115	-0.014
30	8	0.101	0.115	-0.014
30	9	0.101	0.096	0.005
30	10	0.175	0.152	0.023
50	16	0.101	0.115	-0.014
50	17	0.175	0.096	0.079
50	18	0.138	0.115	0.023
50	19	0.138	0.171	-0.033
50	20	0.138	0.171	-0.033
100	B043	0.175	0.171	0.005
100	B044	0.101	0.152	-0.051
100	B045	0.101	0.152	-0.051
100	B046	0.082	0.115	-0.033
100	B047	0.157	0.152	0.005
100	B048	0.138	0.152	-0.014
100	B049	0.101	0.152	-0.051
100	B050	0.101	0.152	-0.051
100	B051	0.082	0.096	-0.014
100	B052	0.101	0.133	-0.033
100	B053	0.157	0.152	0.005
100	B054	0.175	0.152	0.023
100	B055	0.082	0.133	-0.051
100	B056	0.101	0.152	-0.051
100	B057	0.082	0.096	-0.014
100	B058	0.138	0.115	0.023
100	B059	0.175	0.077	0.098
100	B060	0.250	0.152	0.098
100	B061	0.119	0.133	-0.014
100	B062	0.157	0.174	-0.018
100	B063	0.082	0.152	-0.070
100	B064	0.175	0.226	-0.051
	Max	0.250	0.226	0.098
	Average	0.125	0.138	-0.012
	Min	0.082	0.077	-0.070
	Std Dev	0.038	0.030	0.040

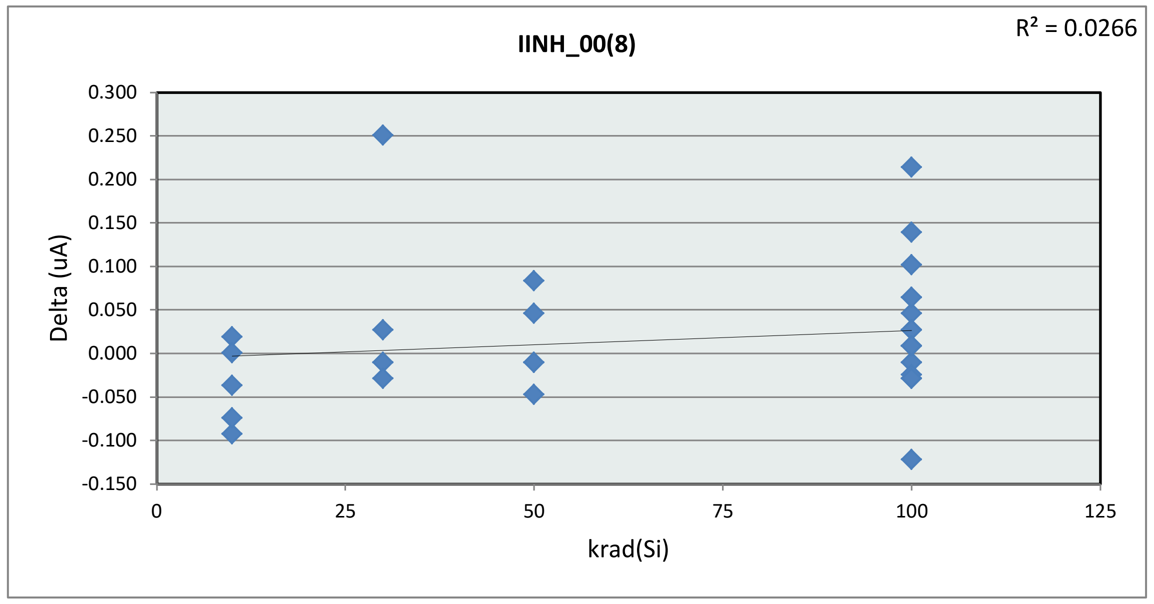


	IINH_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.116	0.096	0.096	0.077
Average	0.142	0.115	0.133	0.143
Max	0.153	0.152	0.171	0.226
UL	18.000	18.000	18.000	18.000

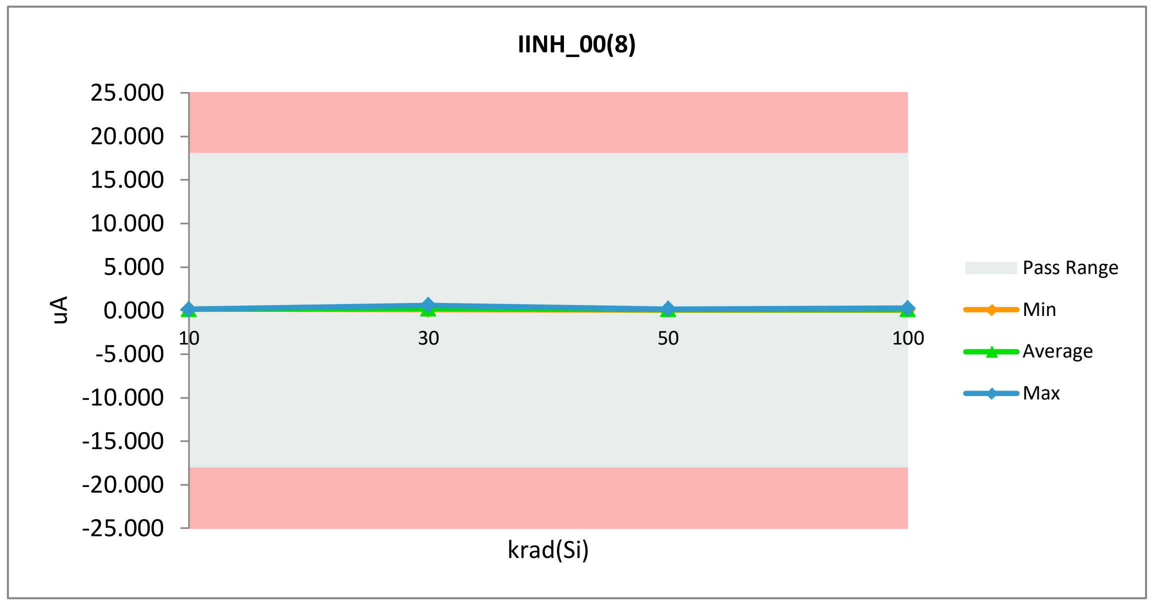


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_00(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.066	0.159	-0.093
10	7	0.160	0.140	0.019
10	8	0.085	0.159	-0.074
10	9	0.122	0.159	-0.037
10	10	0.141	0.140	0.000
30	6	0.854	0.603	0.251
30	7	0.108	0.081	0.027
30	8	0.108	0.118	-0.010
30	9	0.145	0.155	-0.010
30	10	0.089	0.118	-0.029
50	16	0.126	0.081	0.046
50	17	0.126	0.174	-0.047
50	18	0.145	0.062	0.083
50	19	0.108	0.118	-0.010
50	20	0.145	0.155	-0.010
100	B043	0.089	0.081	0.009
100	B044	0.164	0.118	0.046
100	B045	0.070	0.062	0.009
100	B046	0.145	0.118	0.027
100	B047	0.089	0.099	-0.010
100	B048	0.145	0.118	0.027
100	B049	0.145	0.137	0.009
100	B050	0.164	0.062	0.102
100	B051	0.276	0.137	0.139
100	B052	0.126	0.137	-0.010
100	B053	0.108	0.137	-0.029
100	B054	0.126	0.155	-0.029
100	B055	0.145	0.267	-0.122
100	B056	0.089	0.062	0.027
100	B057	0.145	0.118	0.027
100	B058	0.145	0.137	0.009
100	B059	0.126	0.062	0.064
100	B060	0.089	0.081	0.009
100	B061	0.126	0.062	0.064
100	B062	0.108	0.133	-0.025
100	B063	0.294	0.081	0.214
100	B064	0.089	0.118	-0.029
	Max	0.854	0.603	0.251
	Average	0.150	0.132	0.017
	Min	0.066	0.062	-0.122
	Std Dev	0.128	0.090	0.072



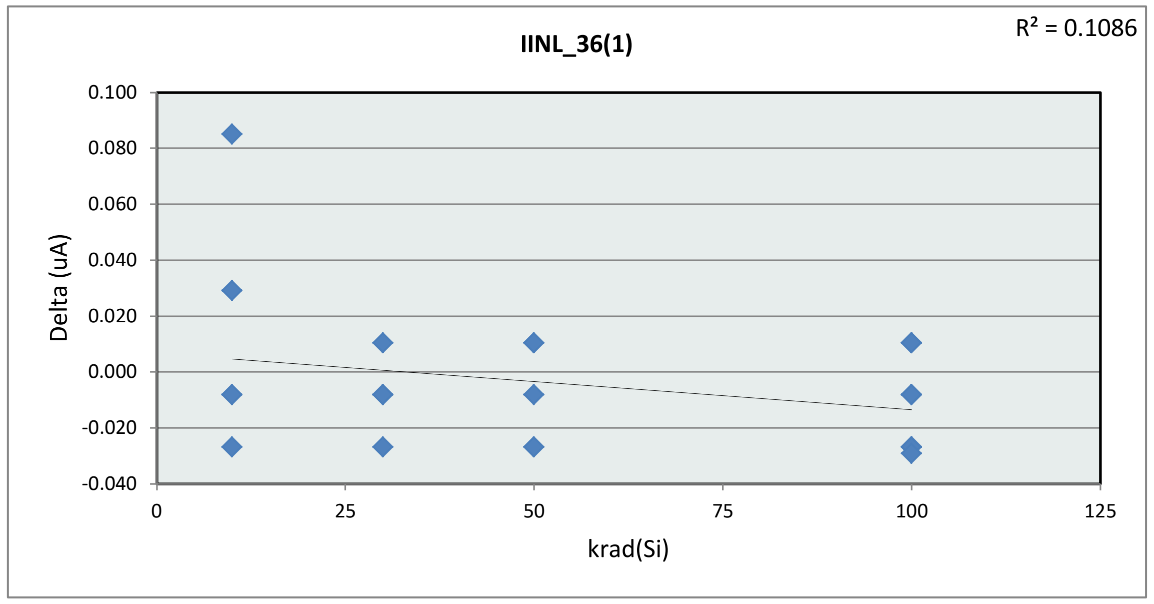
	IINH_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.140	0.081	0.062	0.062
Average	0.152	0.215	0.118	0.113
Max	0.159	0.603	0.174	0.267
UL	18.000	18.000	18.000	18.000



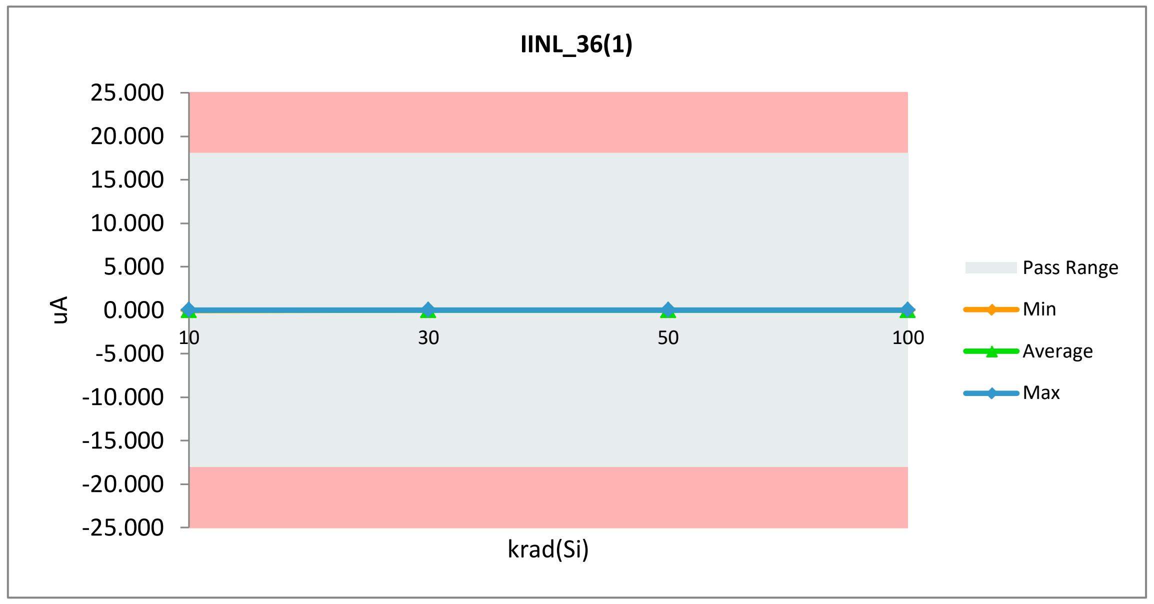
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINL_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	0.018	0.026	-0.008
10	7	-0.001	-0.030	0.029
10	8	-0.001	0.007	-0.008
10	9	0.018	-0.067	0.085
10	10	-0.001	0.026	-0.027
30	6	0.013	0.003	0.010
30	7	-0.006	0.021	-0.027
30	8	-0.006	0.003	-0.008
30	9	0.013	0.021	-0.008
30	10	-0.006	0.003	-0.008
50	16	0.013	0.021	-0.008
50	17	-0.006	0.021	-0.027
50	18	0.013	0.003	0.010
50	19	-0.006	0.021	-0.027
50	20	0.013	0.003	0.010
100	B043	-0.006	0.003	-0.008
100	B044	-0.006	0.021	-0.027
100	B045	0.013	0.021	-0.008
100	B046	-0.006	0.021	-0.027
100	B047	0.013	0.003	0.010
100	B048	-0.006	0.021	-0.027
100	B049	-0.006	0.021	-0.027
100	B050	0.013	0.003	0.010
100	B051	-0.006	0.021	-0.027
100	B052	0.013	0.021	-0.008
100	B053	0.013	0.003	0.010
100	B054	-0.006	0.021	-0.027
100	B055	-0.006	0.021	-0.027
100	B056	-0.006	0.021	-0.027
100	B057	0.013	0.021	-0.008
100	B058	0.013	0.021	-0.008
100	B059	0.013	0.003	0.010
100	B060	-0.006	0.021	-0.027
100	B061	-0.006	0.003	-0.008
100	B062	-0.006	0.023	-0.029
100	B063	0.013	0.003	0.010
100	B064	0.013	0.021	-0.008
	Max	0.018	0.026	0.085
	Average	0.003	0.011	-0.008
	Min	-0.006	-0.067	-0.029
	Std Dev	0.009	0.018	0.022

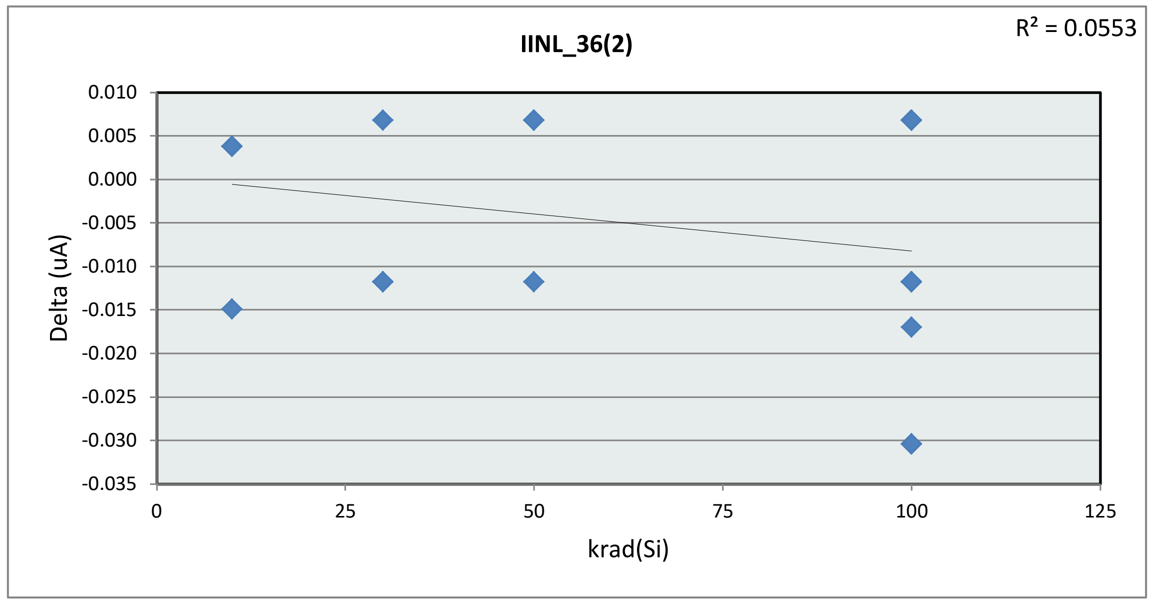


	IINL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.067	0.003	0.003	0.003
Average	-0.008	0.010	0.014	0.015
Max	0.026	0.021	0.021	0.023
UL	18.000	18.000	18.000	18.000

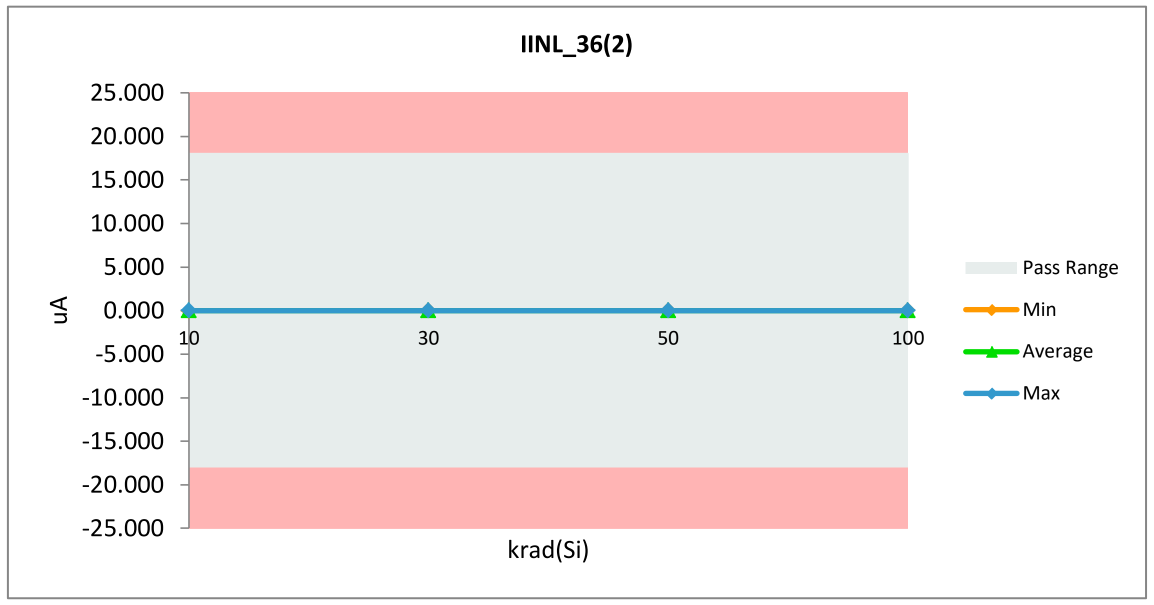


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.011	-0.015	0.004
10	7	-0.011	0.004	-0.015
10	8	-0.011	-0.015	0.004
10	9	-0.011	-0.015	0.004
10	10	-0.011	-0.015	0.004
30	6	-0.023	-0.011	-0.012
30	7	-0.004	0.008	-0.012
30	8	-0.004	0.008	-0.012
30	9	-0.004	-0.011	0.007
30	10	-0.004	0.008	-0.012
50	16	-0.004	-0.011	0.007
50	17	-0.004	-0.011	0.007
50	18	-0.004	-0.011	0.007
50	19	-0.004	-0.011	0.007
50	20	-0.023	-0.011	-0.012
100	B043	-0.023	0.008	-0.030
100	B044	-0.023	-0.011	-0.012
100	B045	-0.004	0.008	-0.012
100	B046	-0.004	0.008	-0.012
100	B047	-0.023	-0.011	-0.012
100	B048	-0.004	-0.011	0.007
100	B049	-0.023	0.008	-0.030
100	B050	-0.004	-0.011	0.007
100	B051	-0.004	-0.011	0.007
100	B052	-0.004	-0.011	0.007
100	B053	-0.004	-0.011	0.007
100	B054	-0.004	-0.011	0.007
100	B055	-0.004	-0.011	0.007
100	B056	-0.004	-0.011	0.007
100	B057	-0.004	0.008	-0.012
100	B058	-0.023	0.008	-0.030
100	B059	-0.023	0.008	-0.030
100	B060	-0.004	0.008	-0.012
100	B061	-0.023	-0.011	-0.012
100	B062	-0.004	0.013	-0.017
100	B063	-0.023	0.008	-0.030
100	B064	-0.004	-0.011	0.007
	Max	-0.004	0.013	0.007
	Average	-0.010	-0.004	-0.006
	Min	-0.023	-0.015	-0.030
	Std Dev	0.008	0.010	0.013



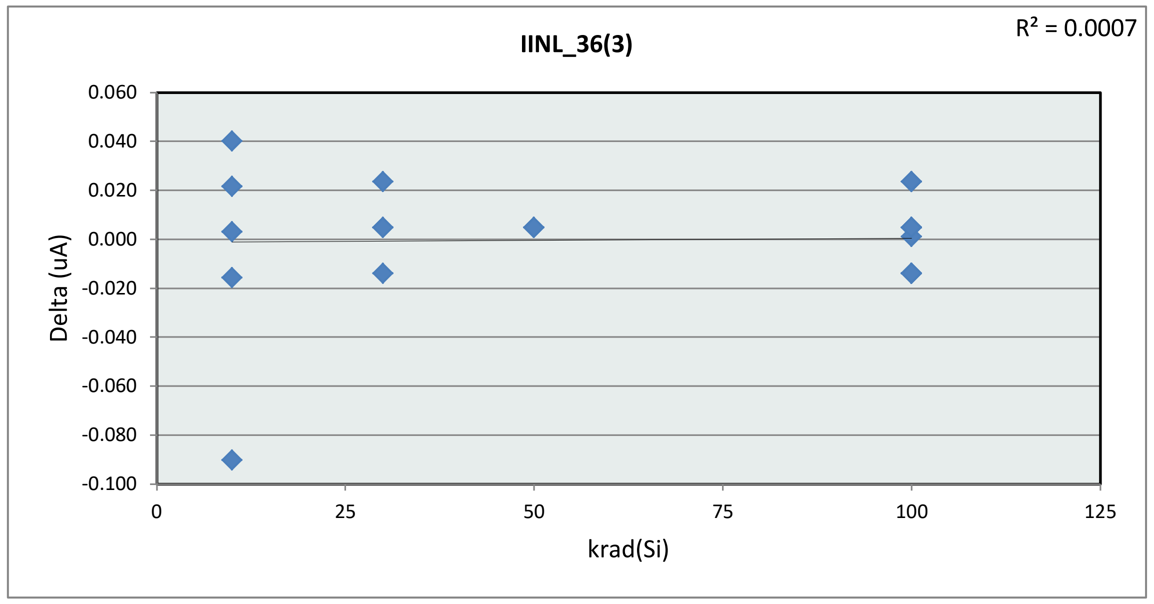
	IINL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.015	-0.011	-0.011	-0.011
Average	-0.011	0.000	-0.011	-0.002
Max	0.004	0.008	-0.011	0.013
UL	18.000	18.000	18.000	18.000



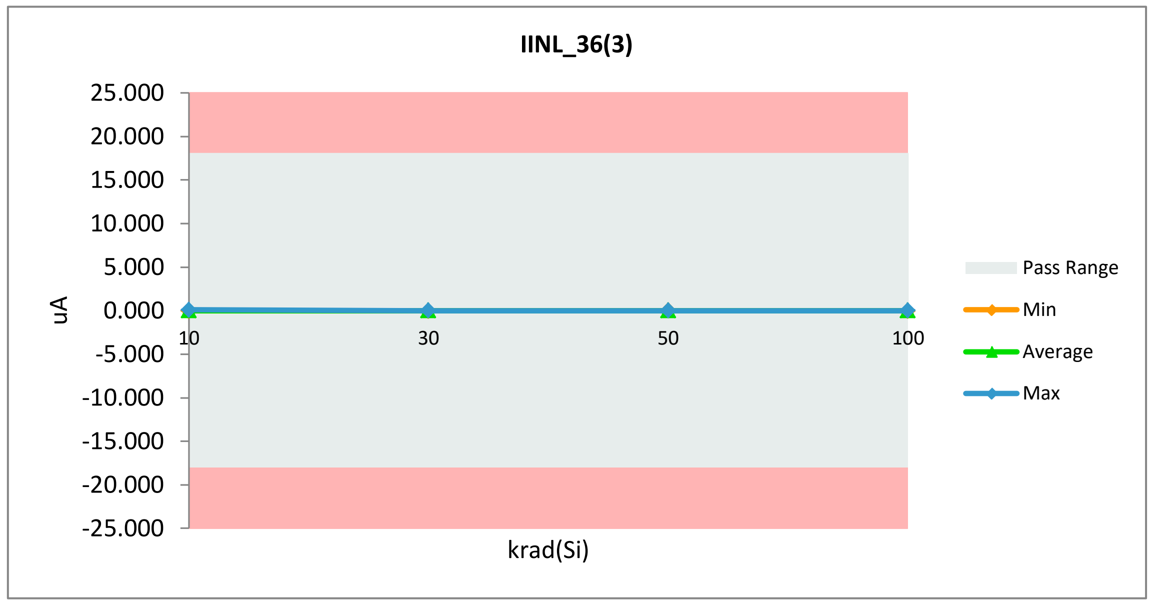
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINL_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.007	0.004	0.003
10	7	-0.011	0.079	-0.090
10	8	0.007	-0.033	0.040
10	9	-0.011	0.004	-0.016
10	10	-0.011	-0.033	0.022
30	6	0.008	-0.016	0.023
30	7	-0.011	0.003	-0.014
30	8	0.008	0.003	0.005
30	9	0.008	0.003	0.005
30	10	0.008	0.003	0.005
50	16	0.008	0.003	0.005
50	17	0.008	0.003	0.005
50	18	0.008	0.003	0.005
50	19	0.008	0.003	0.005
50	20	0.008	0.003	0.005
100	B043	-0.011	0.003	-0.014
100	B044	0.008	0.003	0.005
100	B045	-0.011	0.003	-0.014
100	B046	0.008	-0.016	0.023
100	B047	0.008	0.003	0.005
100	B048	-0.011	0.003	-0.014
100	B049	-0.011	0.003	-0.014
100	B050	0.008	0.003	0.005
100	B051	0.008	-0.016	0.023
100	B052	0.008	0.003	0.005
100	B053	-0.011	0.003	-0.014
100	B054	0.008	0.003	0.005
100	B055	0.008	0.003	0.005
100	B056	0.008	0.003	0.005
100	B057	-0.011	0.003	-0.014
100	B058	-0.011	0.003	-0.014
100	B059	0.008	0.003	0.005
100	B060	-0.011	0.003	-0.014
100	B061	-0.011	0.003	-0.014
100	B062	0.008	0.007	0.001
100	B063	0.008	0.003	0.005
100	B064	0.008	-0.016	0.023
	Max	0.008	0.079	0.040
	Average	0.001	0.001	0.000
	Min	-0.011	-0.033	-0.090
	Std Dev	0.009	0.016	0.020

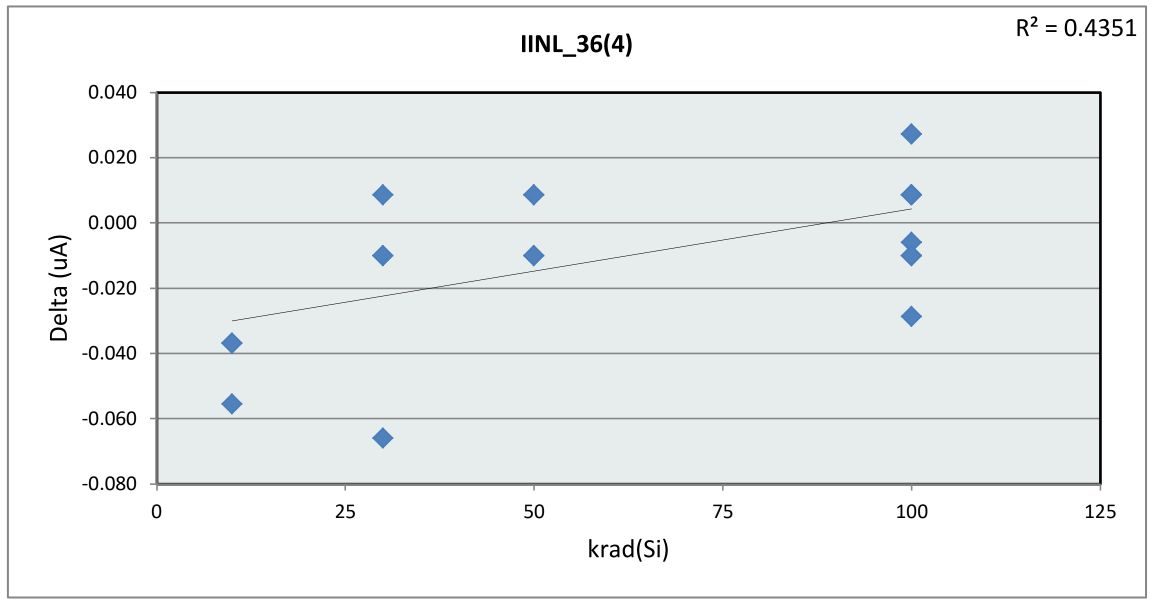


	IINL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.033	-0.016	0.003	-0.016
Average	0.004	-0.001	0.003	0.000
Max	0.079	0.003	0.003	0.007
UL	18.000	18.000	18.000	18.000

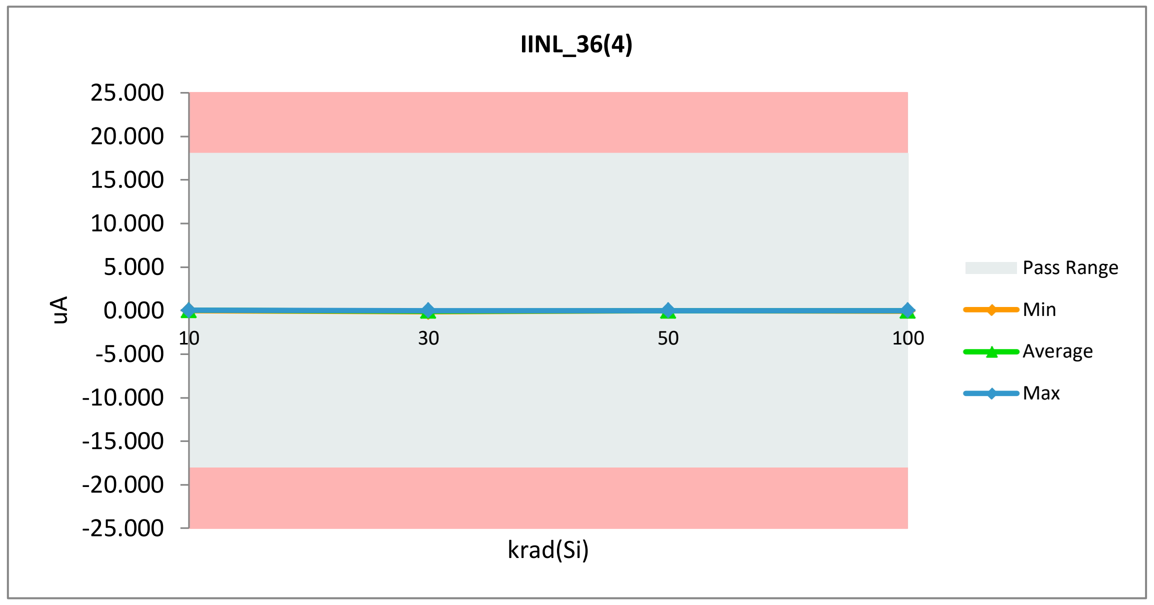


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.008	0.029	-0.037
10	7	-0.027	0.010	-0.037
10	8	-0.027	0.029	-0.056
10	9	-0.027	0.010	-0.037
10	10	-0.027	0.010	-0.037
30	6	-0.228	-0.162	-0.066
30	7	-0.023	-0.013	-0.010
30	8	-0.023	-0.013	-0.010
30	9	-0.023	-0.031	0.009
30	10	-0.023	-0.013	-0.010
50	16	-0.023	-0.031	0.009
50	17	-0.023	-0.031	0.009
50	18	-0.023	-0.013	-0.010
50	19	-0.023	-0.013	-0.010
50	20	-0.023	-0.013	-0.010
100	B043	-0.023	-0.031	0.009
100	B044	-0.023	-0.031	0.009
100	B045	-0.023	-0.031	0.009
100	B046	-0.023	-0.031	0.009
100	B047	-0.023	-0.031	0.009
100	B048	-0.023	-0.031	0.009
100	B049	-0.023	-0.050	0.027
100	B050	-0.023	-0.031	0.009
100	B051	-0.060	-0.031	-0.029
100	B052	-0.023	-0.031	0.009
100	B053	-0.023	-0.013	-0.010
100	B054	-0.023	-0.013	-0.010
100	B055	-0.023	-0.050	0.027
100	B056	-0.023	-0.031	0.009
100	B057	-0.023	-0.031	0.009
100	B058	-0.023	-0.031	0.009
100	B059	-0.023	-0.013	-0.010
100	B060	-0.023	-0.013	-0.010
100	B061	-0.023	-0.031	0.009
100	B062	-0.023	-0.017	-0.006
100	B063	-0.041	-0.031	-0.010
100	B064	-0.023	-0.013	-0.010
	Max	-0.008	0.029	0.027
	Average	-0.030	-0.023	-0.007
	Min	-0.228	-0.162	-0.066
	Std Dev	0.034	0.030	0.021



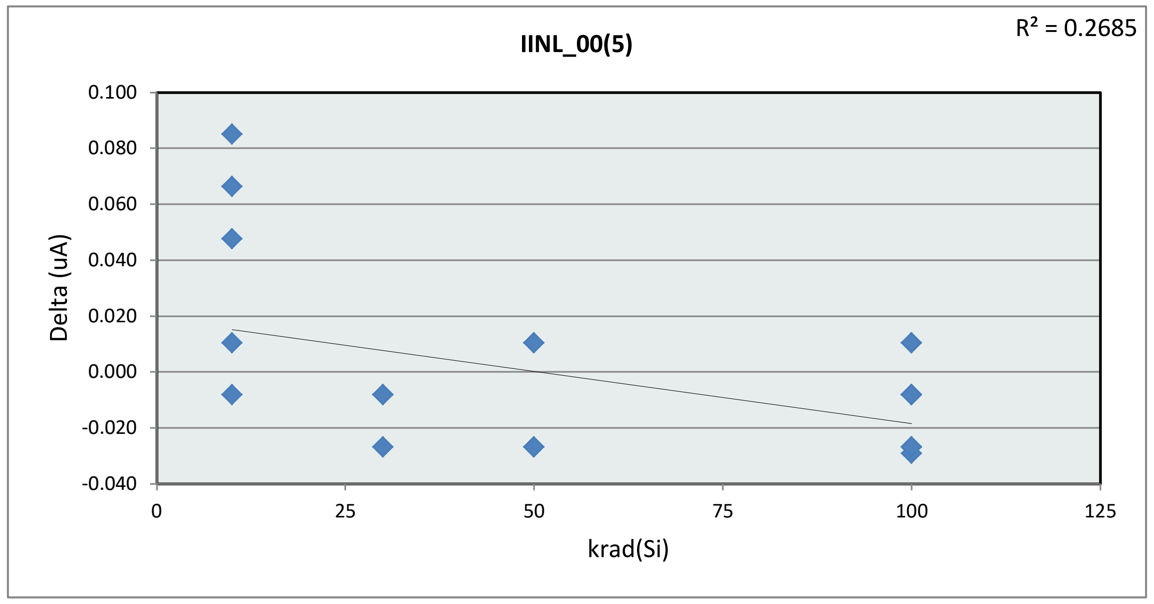
	IINL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.010	-0.162	-0.031	-0.050
Average	0.017	-0.046	-0.020	-0.028
Max	0.029	-0.013	-0.013	-0.013
UL	18.000	18.000	18.000	18.000



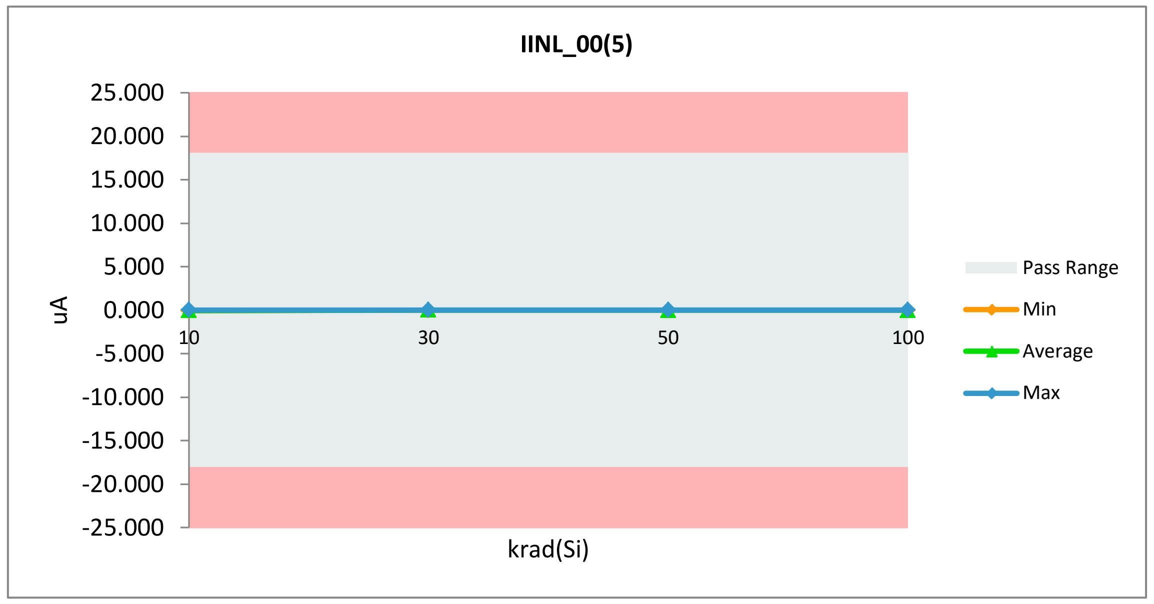
HDR UnBiased TID Report
SN55LVCP22A-SP

	IINL_00(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.001	-0.011	0.010
10	7	0.018	-0.067	0.085
10	8	0.018	0.026	-0.008
10	9	-0.001	-0.067	0.066
10	10	0.018	-0.030	0.048
30	6	-0.006	0.021	-0.027
30	7	0.013	0.021	-0.008
30	8	-0.006	0.021	-0.027
30	9	-0.006	0.003	-0.008
30	10	0.013	0.021	-0.008
50	16	-0.006	0.021	-0.027
50	17	0.013	0.003	0.010
50	18	-0.006	0.021	-0.027
50	19	0.013	0.003	0.010
50	20	-0.006	0.021	-0.027
100	B043	-0.006	0.021	-0.027
100	B044	-0.006	0.021	-0.027
100	B045	0.013	0.021	-0.008
100	B046	-0.006	0.003	-0.008
100	B047	-0.006	0.021	-0.027
100	B048	-0.006	0.021	-0.027
100	B049	0.013	0.003	0.010
100	B050	-0.006	0.021	-0.027
100	B051	0.013	0.021	-0.008
100	B052	-0.006	0.003	-0.008
100	B053	-0.006	0.021	-0.027
100	B054	-0.006	0.003	-0.008
100	B055	0.013	0.021	-0.008
100	B056	0.013	0.003	0.010
100	B057	-0.006	0.021	-0.027
100	B058	-0.006	0.021	-0.027
100	B059	-0.006	0.003	-0.008
100	B060	-0.006	0.021	-0.027
100	B061	-0.006	0.003	-0.008
100	B062	-0.006	0.023	-0.029
100	B063	-0.006	0.021	-0.027
100	B064	-0.006	0.003	-0.008
	Max	0.018	0.026	0.085
	Average	0.001	0.009	-0.008
	Min	-0.006	-0.067	-0.029
	Std Dev	0.009	0.022	0.026

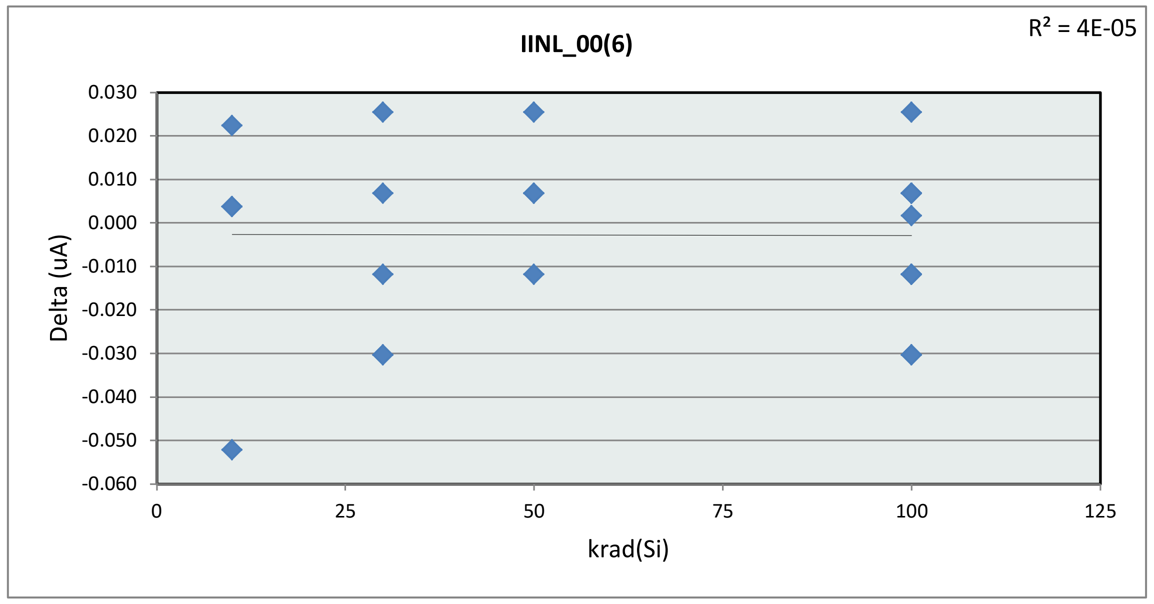


	IINL_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.067	0.003	0.003	0.003
Average	-0.030	0.017	0.014	0.014
Max	0.026	0.021	0.021	0.023
UL	18.000	18.000	18.000	18.000

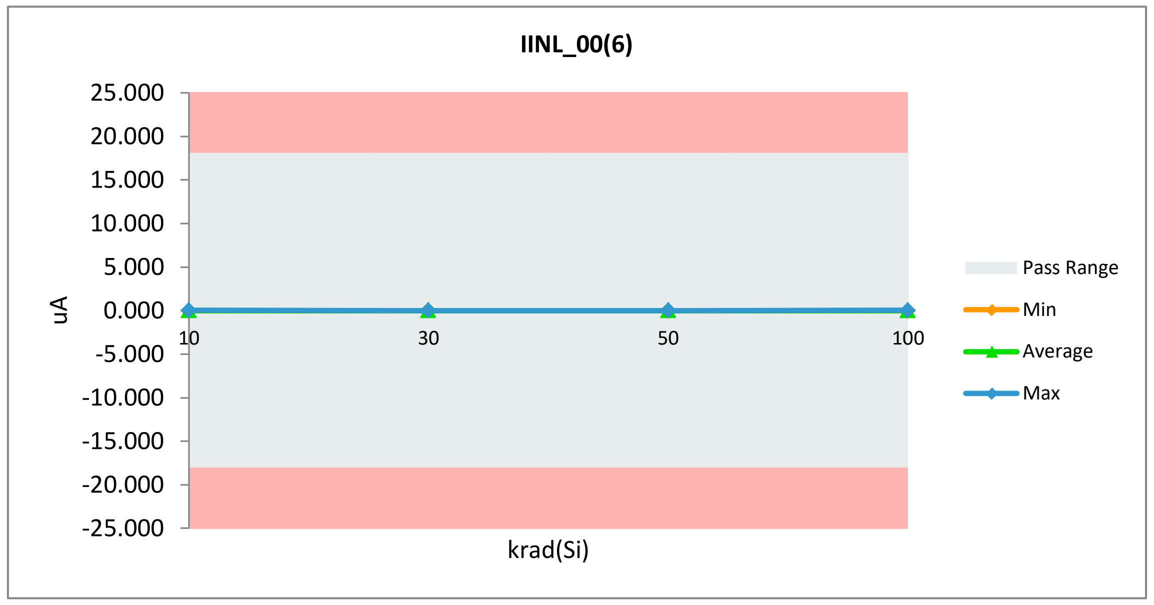


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_00(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.011	-0.015	0.004
10	7	-0.011	-0.015	0.004
10	8	0.007	-0.015	0.022
10	9	-0.011	-0.015	0.004
10	10	-0.011	0.041	-0.052
30	6	0.014	-0.011	0.025
30	7	-0.023	0.008	-0.030
30	8	-0.023	0.008	-0.030
30	9	-0.004	0.008	-0.012
30	10	-0.004	-0.011	0.007
50	16	-0.004	-0.011	0.007
50	17	-0.004	-0.011	0.007
50	18	0.014	-0.011	0.025
50	19	-0.023	-0.030	0.007
50	20	-0.004	0.008	-0.012
100	B043	-0.004	-0.011	0.007
100	B044	-0.004	-0.011	0.007
100	B045	-0.004	-0.011	0.007
100	B046	-0.023	-0.011	-0.012
100	B047	-0.004	0.008	-0.012
100	B048	-0.004	-0.011	0.007
100	B049	-0.004	0.026	-0.030
100	B050	-0.004	-0.011	0.007
100	B051	-0.023	-0.011	-0.012
100	B052	-0.004	-0.030	0.025
100	B053	-0.023	-0.011	-0.012
100	B054	-0.004	0.008	-0.012
100	B055	-0.004	-0.011	0.007
100	B056	-0.004	0.008	-0.012
100	B057	-0.004	0.026	-0.030
100	B058	-0.004	0.008	-0.012
100	B059	-0.004	-0.011	0.007
100	B060	-0.023	0.008	-0.030
100	B061	-0.023	-0.030	0.007
100	B062	0.014	0.013	0.002
100	B063	0.014	0.008	0.007
100	B064	-0.004	-0.011	0.007
	Max	0.014	0.041	0.025
	Average	-0.007	-0.004	-0.003
	Min	-0.023	-0.030	-0.052
	Std Dev	0.011	0.016	0.018

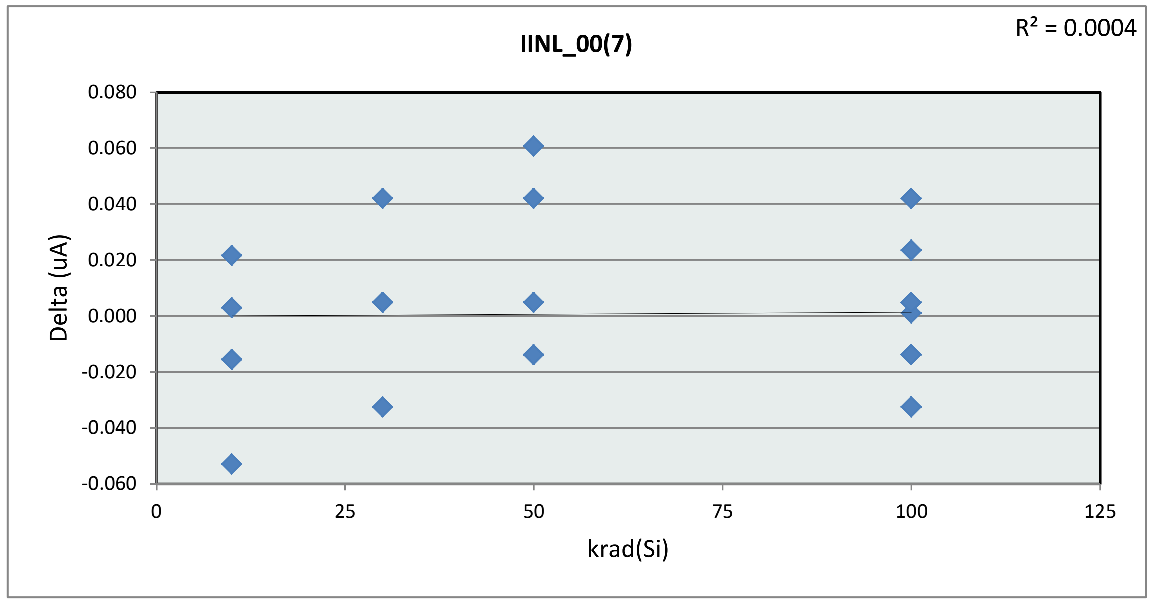


	IINL_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.015	-0.011	-0.030	-0.030
Average	-0.004	0.000	-0.011	-0.003
Max	0.041	0.008	0.008	0.026
UL	18.000	18.000	18.000	18.000

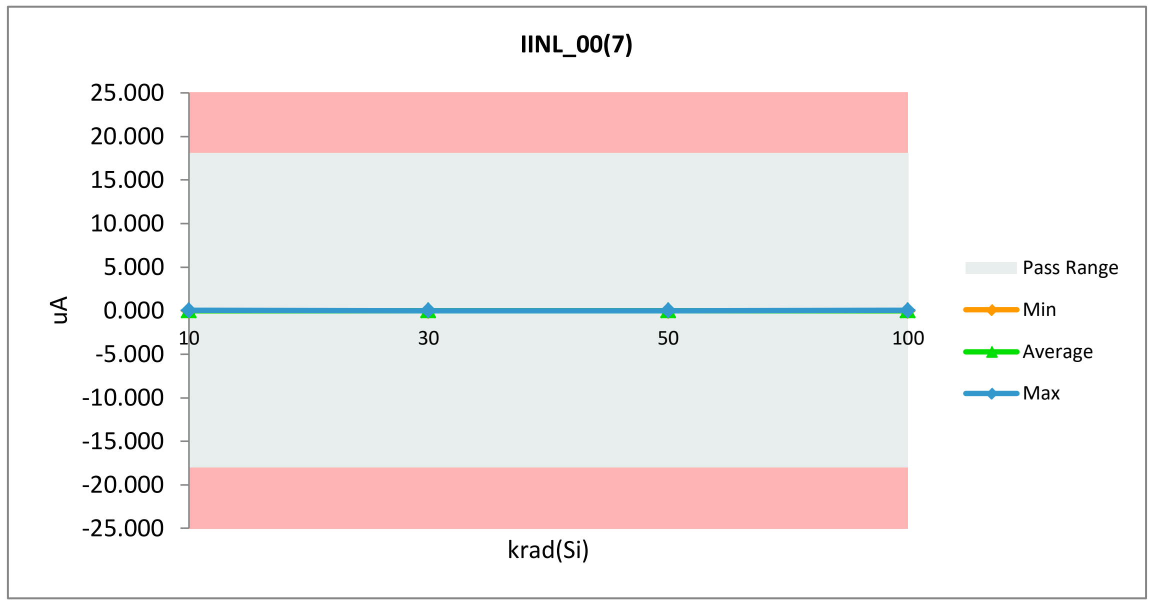


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_00(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.026	0.042	-0.016
10	7	-0.011	-0.014	0.003
10	8	-0.030	0.023	-0.053
10	9	-0.011	-0.033	0.022
10	10	-0.011	0.004	-0.016
30	6	-0.011	-0.016	0.005
30	7	0.008	0.003	0.005
30	8	0.008	-0.035	0.042
30	9	-0.030	0.003	-0.033
30	10	-0.011	-0.016	0.005
50	16	0.026	-0.035	0.061
50	17	0.008	0.003	0.005
50	18	-0.011	0.003	-0.014
50	19	-0.011	0.003	-0.014
50	20	0.026	-0.016	0.042
100	B043	-0.030	0.003	-0.033
100	B044	-0.011	0.003	-0.014
100	B045	-0.011	-0.016	0.005
100	B046	0.026	-0.016	0.042
100	B047	-0.011	-0.016	0.005
100	B048	-0.011	-0.016	0.005
100	B049	0.008	-0.016	0.023
100	B050	0.008	-0.016	0.023
100	B051	0.008	-0.016	0.023
100	B052	-0.011	-0.016	0.005
100	B053	-0.030	-0.016	-0.014
100	B054	-0.011	0.021	-0.033
100	B055	0.008	0.021	-0.014
100	B056	0.008	0.021	-0.014
100	B057	0.008	0.021	-0.014
100	B058	-0.030	0.003	-0.033
100	B059	-0.011	0.003	-0.014
100	B060	0.008	0.003	0.005
100	B061	-0.011	0.003	-0.014
100	B062	0.008	0.007	0.001
100	B063	0.008	0.003	0.005
100	B064	0.026	-0.016	0.042
	Max	0.026	0.042	0.061
	Average	-0.003	-0.003	0.001
	Min	-0.030	-0.035	-0.053
	Std Dev	0.017	0.017	0.025

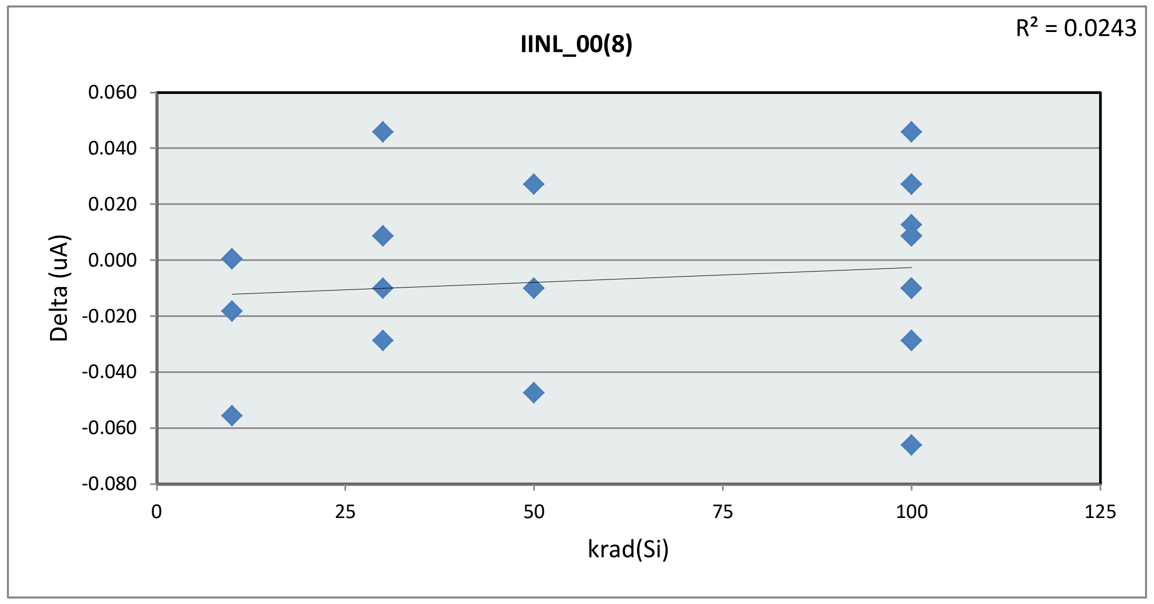


	IINL_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.033	-0.035	-0.035	-0.016
Average	0.004	-0.012	-0.008	-0.002
Max	0.042	0.003	0.003	0.021
UL	18.000	18.000	18.000	18.000

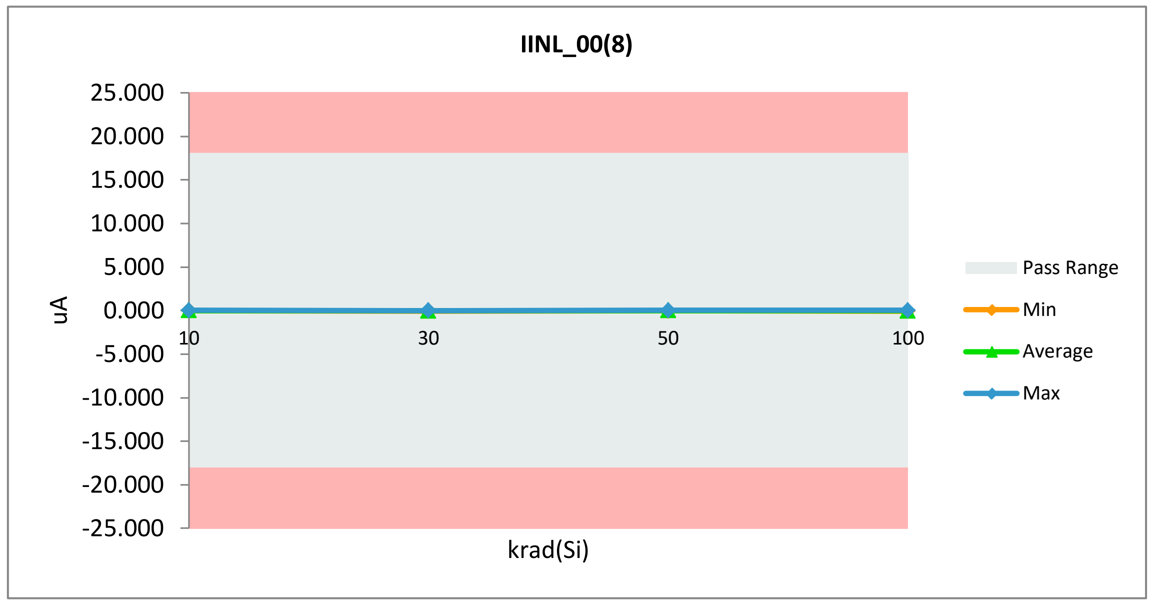


HDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_00(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	0.029	0.029	0.000
10	7	-0.008	0.010	-0.018
10	8	-0.046	0.010	-0.056
10	9	-0.008	0.010	-0.018
10	10	0.010	0.010	0.000
30	6	0.014	-0.031	0.046
30	7	-0.041	-0.031	-0.010
30	8	-0.041	-0.050	0.009
30	9	-0.023	0.006	-0.029
30	10	-0.023	-0.031	0.009
50	16	-0.023	0.025	-0.047
50	17	-0.041	0.006	-0.047
50	18	-0.023	-0.013	-0.010
50	19	0.014	-0.013	0.027
50	20	-0.041	-0.031	-0.010
100	B043	0.014	-0.013	0.027
100	B044	0.014	-0.031	0.046
100	B045	-0.023	-0.031	0.009
100	B046	-0.041	-0.031	-0.010
100	B047	-0.041	-0.031	-0.010
100	B048	-0.023	-0.031	0.009
100	B049	-0.023	-0.031	0.009
100	B050	-0.041	-0.031	-0.010
100	B051	-0.041	-0.031	-0.010
100	B052	-0.041	-0.050	0.009
100	B053	-0.041	-0.031	-0.010
100	B054	-0.041	0.025	-0.066
100	B055	-0.041	-0.013	-0.029
100	B056	-0.041	-0.031	-0.010
100	B057	-0.023	-0.050	0.027
100	B058	-0.023	-0.031	0.009
100	B059	-0.023	0.006	-0.029
100	B060	-0.041	-0.031	-0.010
100	B061	-0.041	-0.031	-0.010
100	B062	0.014	0.002	0.013
100	B063	-0.041	-0.031	-0.010
100	B064	-0.023	-0.031	0.009
	Max	0.029	0.029	0.046
	Average	-0.023	-0.018	-0.006
	Min	-0.046	-0.050	-0.066
	Std Dev	0.022	0.022	0.025

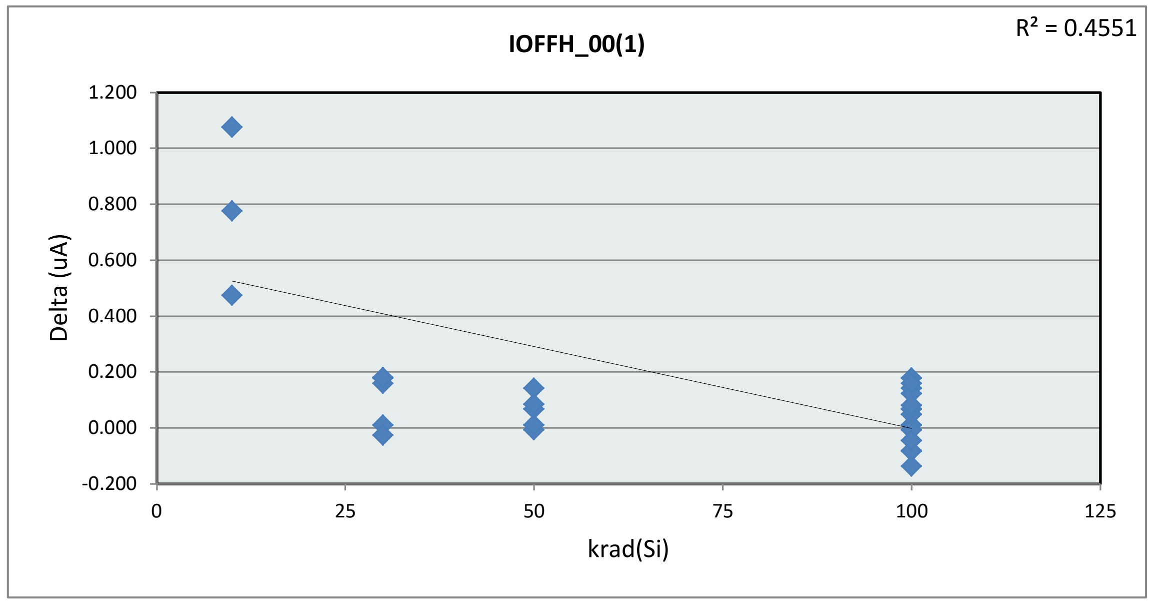


	IINL_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.010	-0.050	-0.031	-0.050
Average	0.014	-0.028	-0.005	-0.026
Max	0.029	0.006	0.025	0.025
UL	18.000	18.000	18.000	18.000

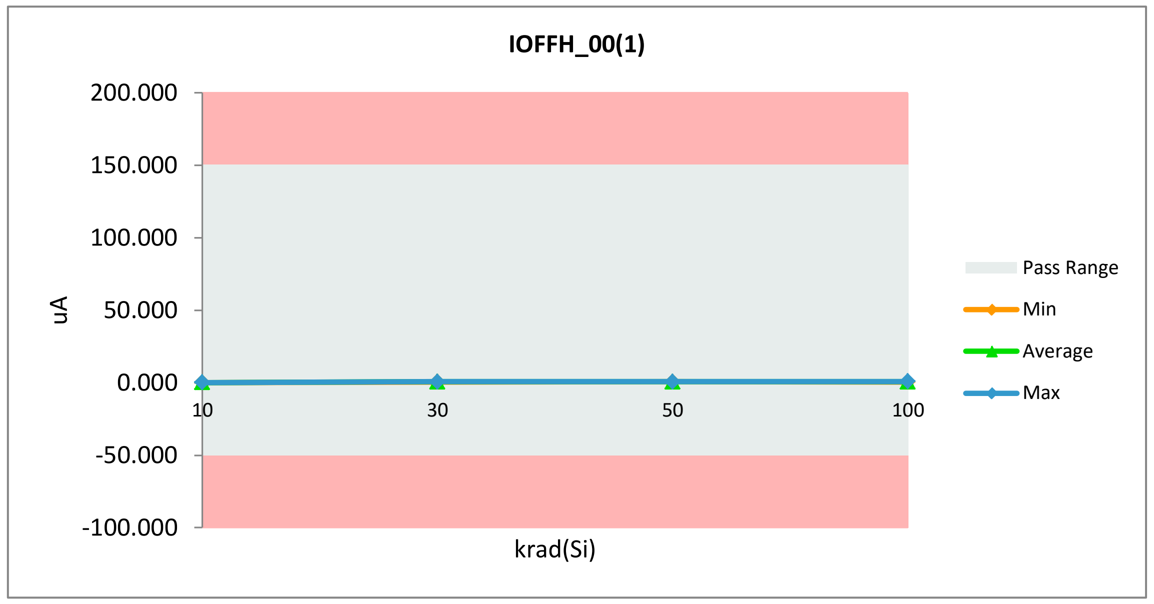


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_00(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.545	0.071	0.474
10	7	1.146	0.071	1.075
10	8	0.845	0.071	0.775
10	9	1.146	0.071	1.075
10	10	1.146	0.071	1.075
30	6	0.766	0.756	0.010
30	7	0.673	0.700	-0.027
30	8	0.692	0.512	0.180
30	9	0.766	0.607	0.159
30	10	0.766	0.588	0.178
50	16	0.673	0.681	-0.008
50	17	0.822	0.681	0.141
50	18	0.692	0.681	0.010
50	19	0.692	0.625	0.066
50	20	0.785	0.700	0.085
100	B043	0.729	0.812	-0.084
100	B044	0.617	0.756	-0.138
100	B045	0.785	0.607	0.178
100	B046	0.729	0.681	0.048
100	B047	0.766	0.625	0.141
100	B048	0.729	0.662	0.066
100	B049	0.617	0.700	-0.083
100	B050	0.803	0.625	0.178
100	B051	0.747	0.625	0.122
100	B052	0.692	0.625	0.066
100	B053	0.673	0.662	0.010
100	B054	0.692	0.625	0.066
100	B055	0.673	0.681	-0.008
100	B056	0.766	0.718	0.048
100	B057	0.692	0.681	0.010
100	B058	0.654	0.662	-0.008
100	B059	0.636	0.569	0.066
100	B060	0.636	0.681	-0.045
100	B061	0.729	0.737	-0.008
100	B062	0.692	0.612	0.080
100	B063	0.636	0.681	-0.045
100	B064	0.729	0.569	0.159
	Max	1.146	0.812	1.075
	Average	0.745	0.581	0.165
	Min	0.545	0.071	-0.138
	Std Dev	0.136	0.212	0.316

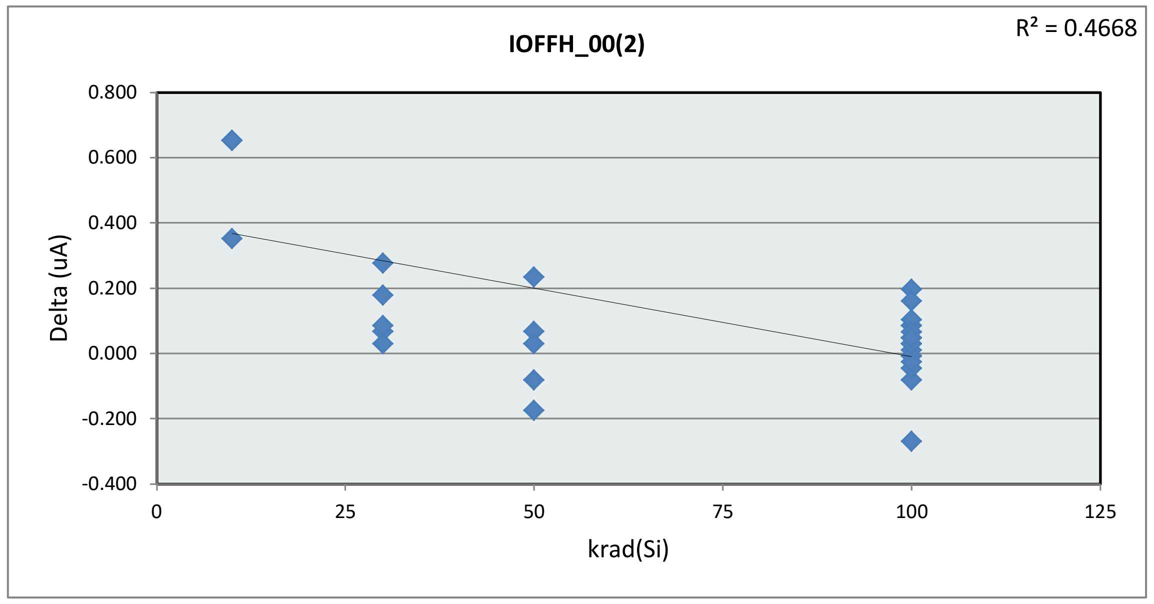


	IOFFH_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.071	0.512	0.625	0.569
Average	0.071	0.632	0.674	0.664
Max	0.071	0.756	0.700	0.812
UL	150.000	150.000	150.000	150.000

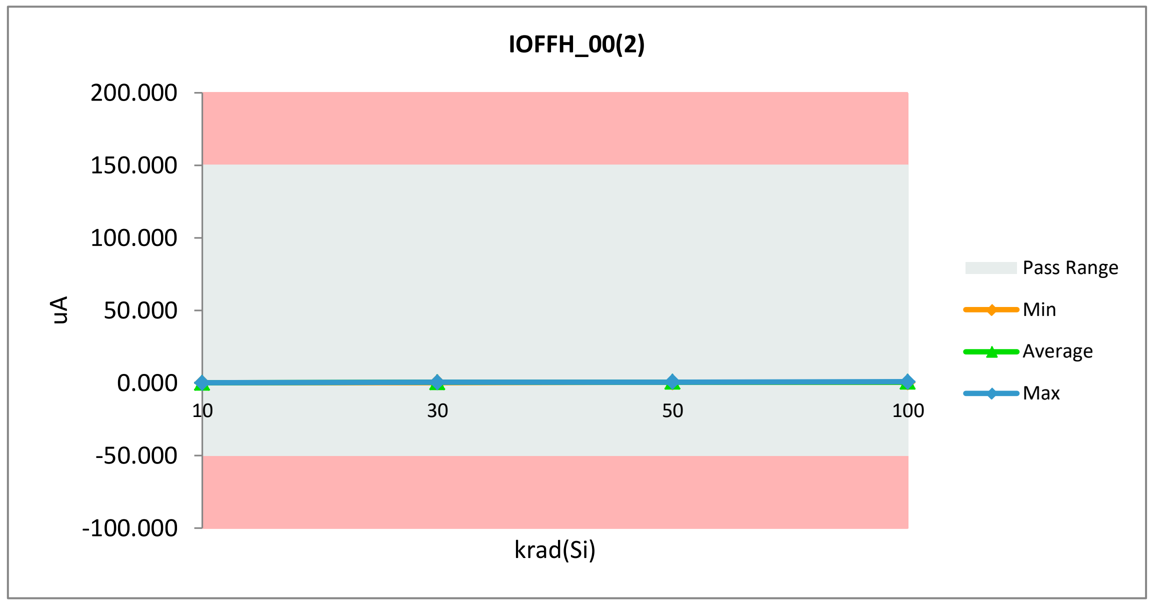


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.835	0.182	0.652
10	7	0.835	0.182	0.652
10	8	0.534	0.182	0.352
10	9	0.835	0.182	0.652
10	10	0.835	0.182	0.652
30	6	0.683	0.617	0.066
30	7	0.665	0.635	0.029
30	8	0.609	0.332	0.277
30	9	0.665	0.580	0.085
30	10	0.814	0.635	0.178
50	16	0.739	0.673	0.066
50	17	0.665	0.747	-0.082
50	18	0.814	0.580	0.234
50	19	0.776	0.747	0.029
50	20	0.627	0.803	-0.175
100	B043	0.665	0.934	-0.269
100	B044	0.776	0.747	0.029
100	B045	0.665	0.654	0.011
100	B046	0.646	0.728	-0.082
100	B047	0.758	0.710	0.048
100	B048	0.702	0.617	0.085
100	B049	0.702	0.784	-0.082
100	B050	0.646	0.691	-0.045
100	B051	0.646	0.598	0.048
100	B052	0.776	0.580	0.197
100	B053	0.720	0.728	-0.008
100	B054	0.776	0.691	0.085
100	B055	0.683	0.728	-0.045
100	B056	0.627	0.635	-0.008
100	B057	0.739	0.635	0.104
100	B058	0.758	0.598	0.160
100	B059	0.665	0.673	-0.008
100	B060	0.665	0.691	-0.027
100	B061	0.739	0.710	0.029
100	B062	0.665	0.599	0.066
100	B063	0.776	0.747	0.029
100	B064	0.720	0.673	0.048
	Max	0.835	0.934	0.652
	Average	0.715	0.606	0.109
	Min	0.534	0.182	-0.269
	Std Dev	0.074	0.193	0.224



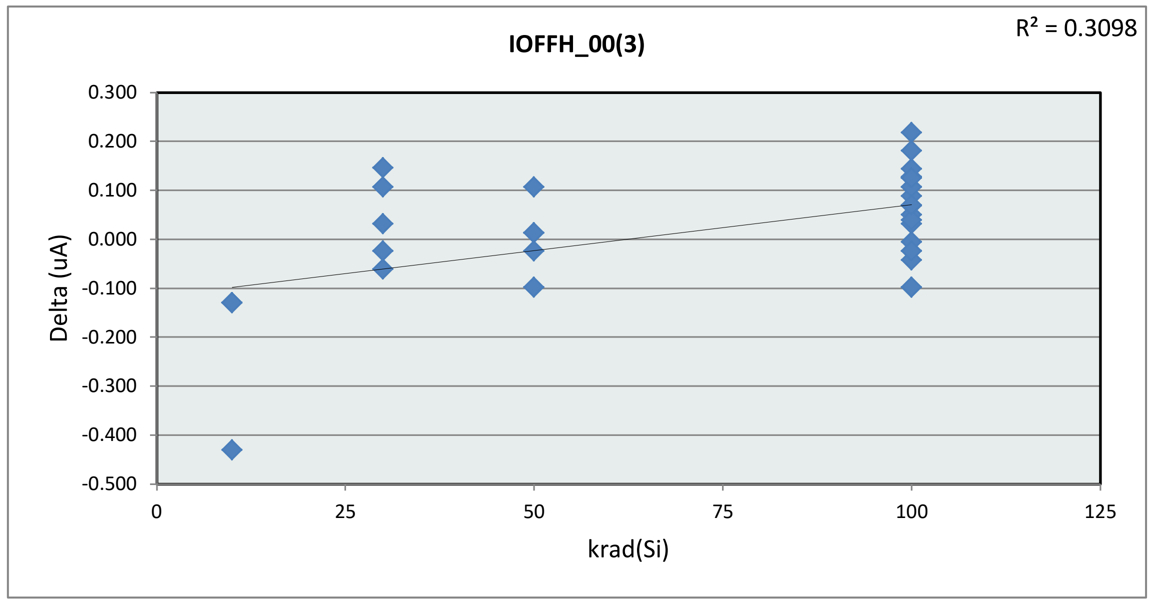
	IOFFH_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.182	0.332	0.580	0.580
Average	0.182	0.560	0.710	0.689
Max	0.182	0.635	0.803	0.934
UL	150.000	150.000	150.000	150.000



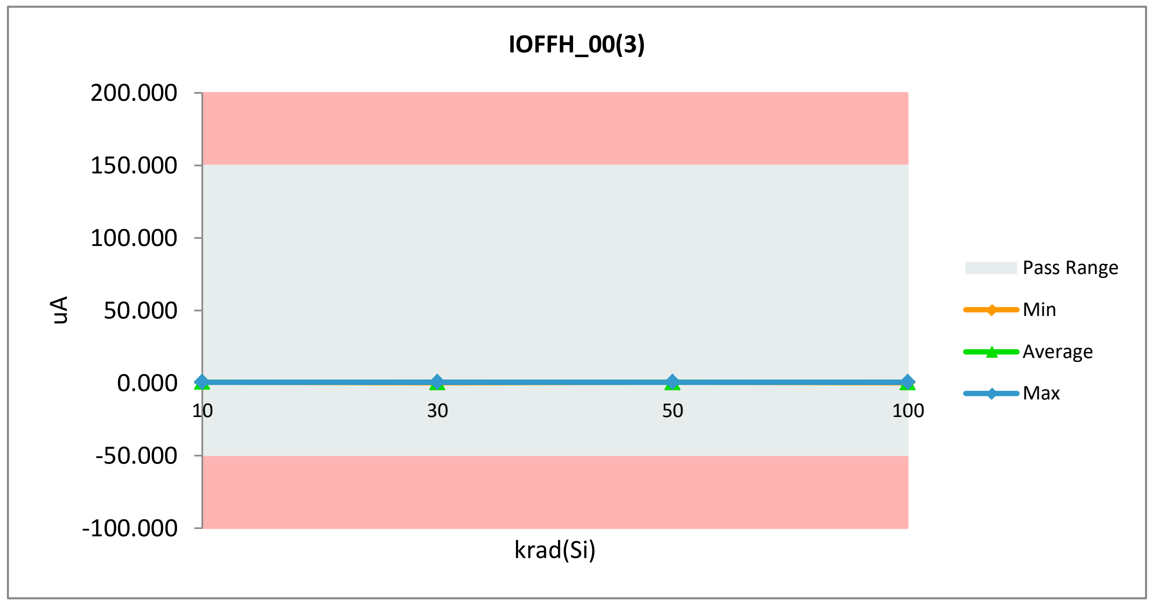
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFH_00(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.716	0.846	-0.129
10	7	0.415	0.846	-0.430
10	8	0.716	0.846	-0.129
10	9	0.716	0.846	-0.129
10	10	0.716	0.846	-0.129
30	6	0.730	0.624	0.106
30	7	0.674	0.642	0.032
30	8	0.618	0.473	0.146
30	9	0.655	0.717	-0.061
30	10	0.618	0.642	-0.024
50	16	0.618	0.642	-0.024
50	17	0.767	0.754	0.013
50	18	0.655	0.642	0.013
50	19	0.600	0.698	-0.099
50	20	0.730	0.624	0.106
100	B043	0.600	0.473	0.127
100	B044	0.581	0.624	-0.043
100	B045	0.767	0.624	0.144
100	B046	0.730	0.698	0.032
100	B047	0.674	0.624	0.050
100	B048	0.655	0.586	0.069
100	B049	0.730	0.624	0.106
100	B050	0.767	0.549	0.218
100	B051	0.674	0.586	0.088
100	B052	0.618	0.717	-0.099
100	B053	0.674	0.549	0.125
100	B054	0.618	0.642	-0.024
100	B055	0.693	0.698	-0.005
100	B056	0.749	0.642	0.106
100	B057	0.767	0.642	0.125
100	B058	0.618	0.549	0.069
100	B059	0.749	0.568	0.181
100	B060	0.655	0.680	-0.024
100	B061	0.767	0.642	0.125
100	B062	0.693	0.654	0.039
100	B063	0.618	0.717	-0.099
100	B064	0.693	0.624	0.069
	Max	0.767	0.846	0.218
	Average	0.677	0.659	0.017
	Min	0.415	0.473	-0.430
	Std Dev	0.072	0.096	0.122

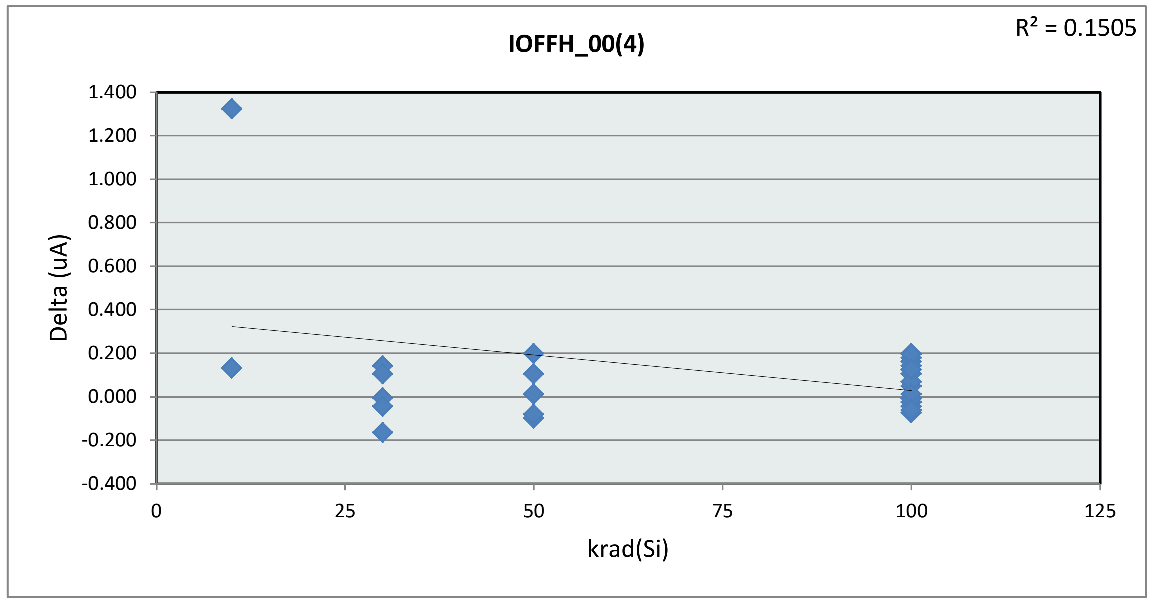


	IOFFH_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.846	0.473	0.624	0.473
Average	0.846	0.620	0.672	0.623
Max	0.846	0.717	0.754	0.717
UL	150.000	150.000	150.000	150.000

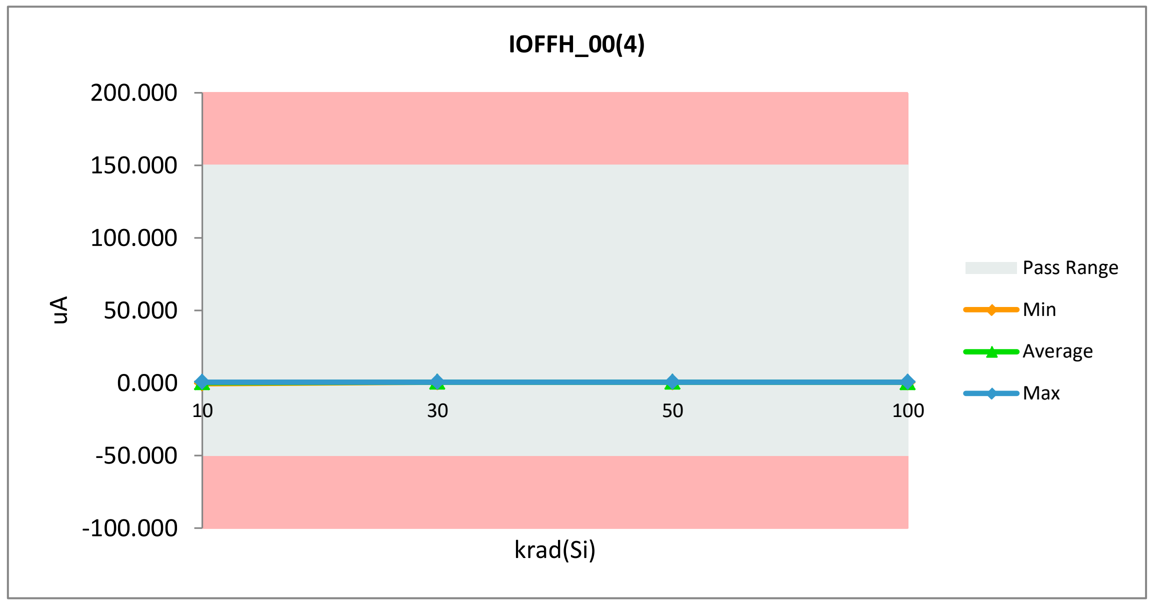


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.919	-0.403	1.322
10	7	0.919	0.787	0.132
10	8	0.919	-0.403	1.322
10	9	0.919	0.787	0.132
10	10	0.919	0.787	0.132
30	6	0.706	0.714	-0.007
30	7	0.781	0.639	0.142
30	8	0.688	0.854	-0.166
30	9	0.706	0.751	-0.044
30	10	0.818	0.714	0.105
50	16	0.595	0.695	-0.100
50	17	0.799	0.602	0.198
50	18	0.706	0.695	0.012
50	19	0.688	0.769	-0.082
50	20	0.781	0.676	0.105
100	B043	0.781	0.854	-0.073
100	B044	0.632	0.658	-0.026
100	B045	0.799	0.639	0.160
100	B046	0.688	0.639	0.049
100	B047	0.781	0.602	0.179
100	B048	0.651	0.695	-0.044
100	B049	0.781	0.639	0.142
100	B050	0.762	0.565	0.198
100	B051	0.688	0.695	-0.007
100	B052	0.595	0.620	-0.026
100	B053	0.669	0.565	0.105
100	B054	0.799	0.676	0.123
100	B055	0.632	0.639	-0.007
100	B056	0.688	0.695	-0.007
100	B057	0.799	0.695	0.105
100	B058	0.781	0.714	0.067
100	B059	0.688	0.620	0.067
100	B060	0.613	0.620	-0.007
100	B061	0.706	0.695	0.012
100	B062	0.781	0.587	0.194
100	B063	0.744	0.620	0.123
100	B064	0.632	0.695	-0.063
	Max	0.919	0.854	1.322
	Average	0.745	0.624	0.121
	Min	0.595	-0.403	-0.166
	Std Dev	0.094	0.259	0.306

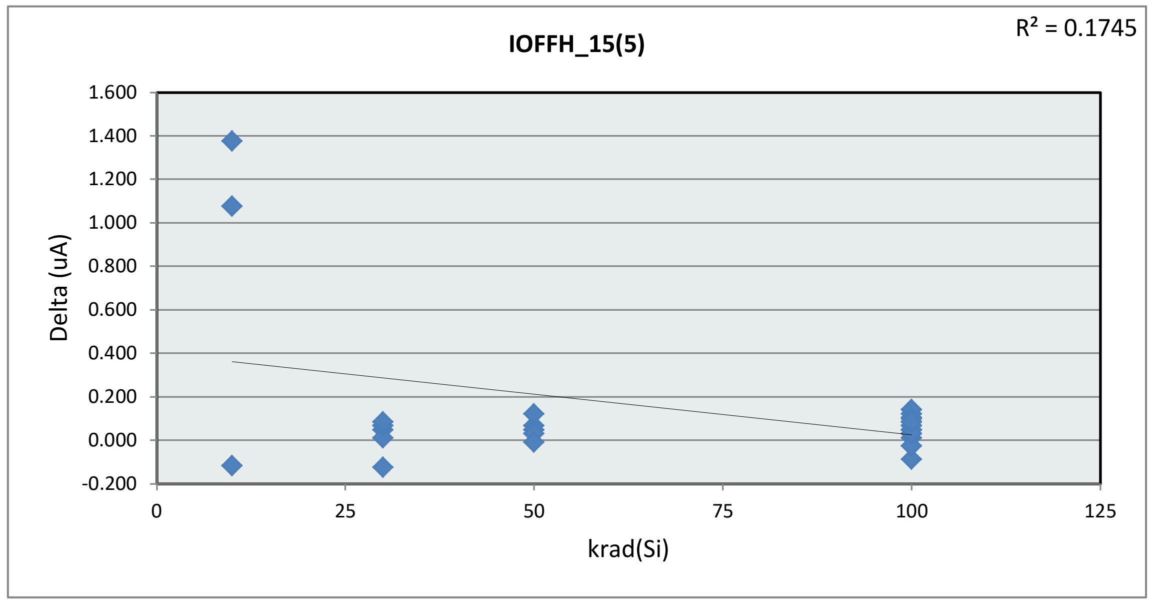


	IOFFH_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.403	0.639	0.602	0.565
Average	0.311	0.734	0.687	0.656
Max	0.787	0.854	0.769	0.854
UL	150.000	150.000	150.000	150.000

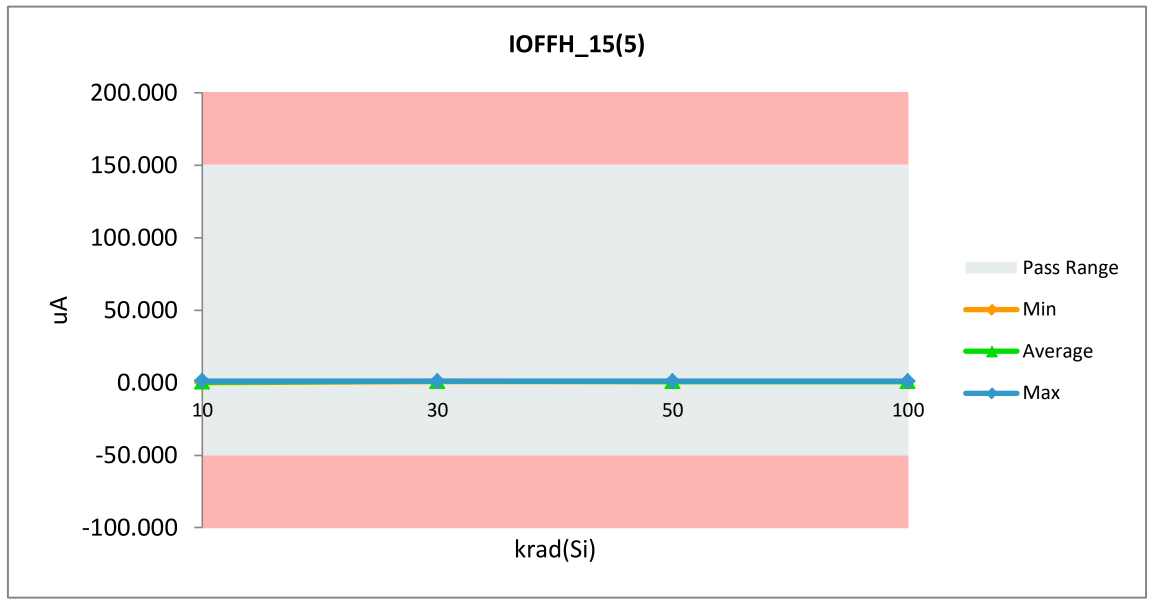


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_15(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.146	0.071	1.075
10	7	1.146	1.262	-0.116
10	8	1.446	0.071	1.375
10	9	1.146	0.071	1.075
10	10	1.146	1.262	-0.116
30	6	1.008	0.960	0.048
30	7	0.971	0.960	0.010
30	8	0.989	1.113	-0.124
30	9	1.008	0.942	0.066
30	10	1.026	0.942	0.085
50	16	0.971	0.904	0.066
50	17	1.045	0.997	0.048
50	18	1.064	0.942	0.122
50	19	1.026	0.997	0.029
50	20	1.008	1.016	-0.008
100	B043	1.026	1.113	-0.087
100	B044	1.026	0.997	0.029
100	B045	1.026	0.923	0.103
100	B046	0.971	0.942	0.029
100	B047	1.008	0.960	0.048
100	B048	1.026	0.960	0.066
100	B049	0.971	0.997	-0.027
100	B050	1.045	0.904	0.141
100	B051	1.026	0.960	0.066
100	B052	1.008	0.960	0.048
100	B053	1.045	0.923	0.122
100	B054	0.989	0.979	0.010
100	B055	0.915	0.942	-0.027
100	B056	0.989	0.942	0.048
100	B057	1.026	0.979	0.048
100	B058	1.026	0.942	0.085
100	B059	1.026	0.942	0.085
100	B060	1.008	0.923	0.085
100	B061	1.101	0.960	0.141
100	B062	1.026	0.928	0.098
100	B063	0.989	0.960	0.029
100	B064	1.026	0.942	0.085
	Max	1.446	1.262	1.375
	Average	1.039	0.908	0.131
	Min	0.915	0.071	-0.124
	Std Dev	0.086	0.265	0.324

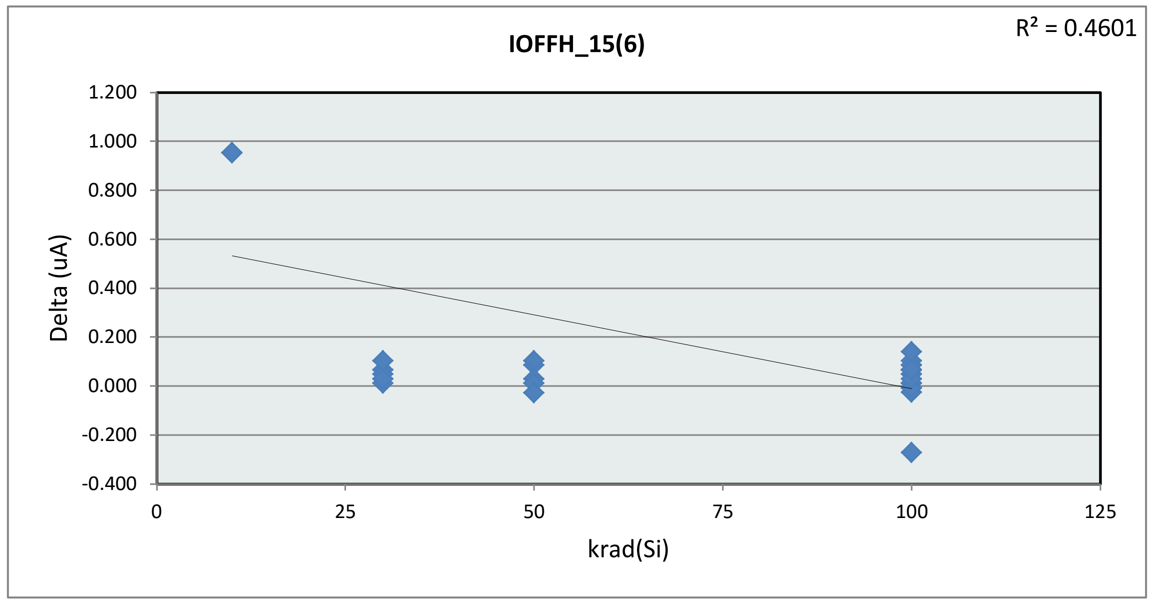


	IOFFH_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.071	0.942	0.904	0.904
Average	0.547	0.983	0.971	0.958
Max	1.262	1.113	1.016	1.113
UL	150.000	150.000	150.000	150.000

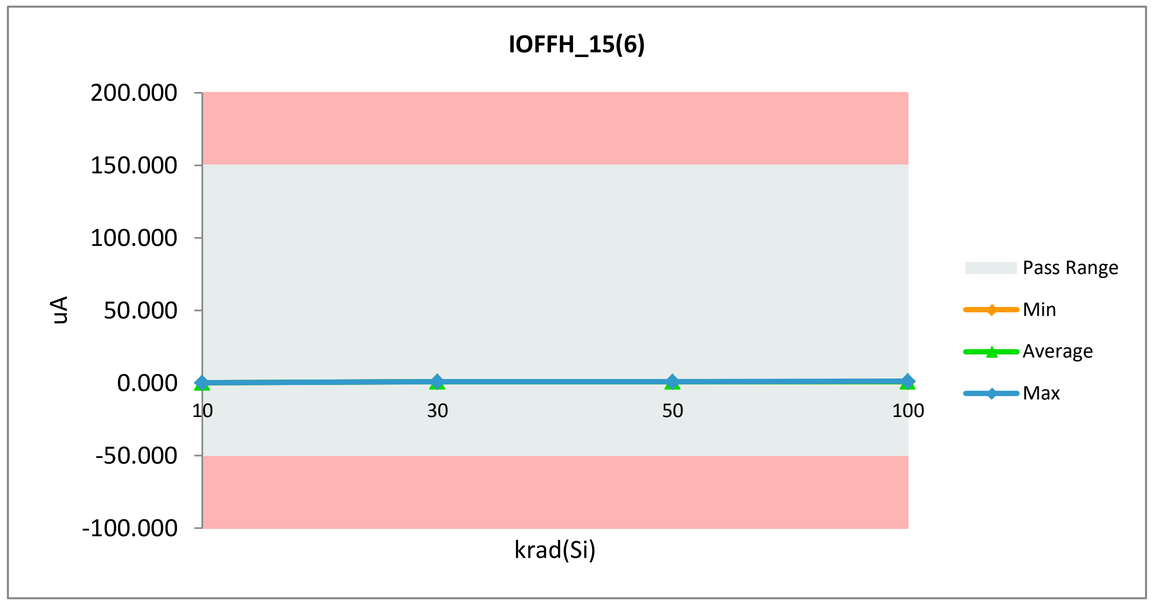


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_15(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.135	0.182	0.953
10	7	1.135	0.182	0.953
10	8	1.135	0.182	0.953
10	9	1.135	0.182	0.953
10	10	1.135	0.182	0.953
30	6	1.000	0.933	0.067
30	7	0.962	0.952	0.011
30	8	0.981	0.934	0.048
30	9	0.981	0.952	0.029
30	10	1.037	0.933	0.104
50	16	0.981	0.896	0.085
50	17	1.018	0.989	0.029
50	18	1.037	0.933	0.104
50	19	1.000	0.989	0.011
50	20	0.981	1.008	-0.027
100	B043	0.962	1.234	-0.272
100	B044	1.000	0.989	0.011
100	B045	1.000	0.933	0.067
100	B046	0.962	0.952	0.011
100	B047	1.037	0.970	0.067
100	B048	1.000	0.952	0.048
100	B049	1.000	0.989	0.011
100	B050	1.018	0.915	0.104
100	B051	0.981	0.989	-0.008
100	B052	0.981	0.970	0.011
100	B053	1.018	0.933	0.085
100	B054	0.962	0.989	-0.027
100	B055	1.000	0.933	0.067
100	B056	0.981	0.933	0.048
100	B057	1.000	1.008	-0.008
100	B058	1.000	0.933	0.067
100	B059	1.037	0.952	0.085
100	B060	0.981	0.915	0.067
100	B061	1.093	0.952	0.141
100	B062	1.000	0.933	0.066
100	B063	1.000	0.970	0.029
100	B064	1.018	0.952	0.067
	Max	1.135	1.234	0.953
	Average	1.018	0.858	0.161
	Min	0.962	0.182	-0.272
	Std Dev	0.053	0.276	0.324



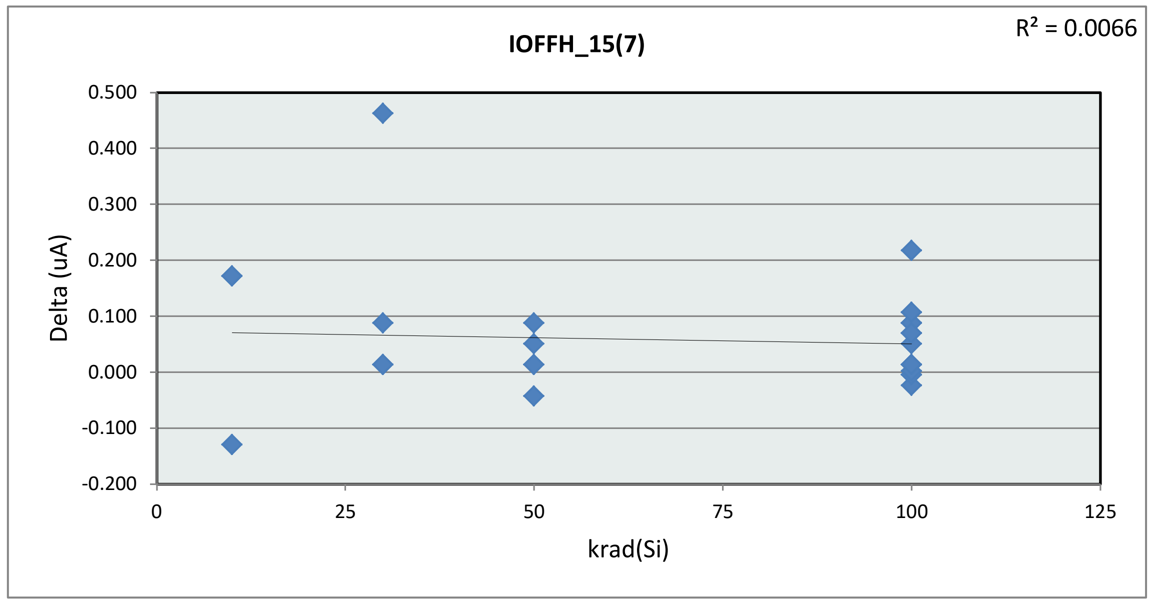
	IOFFH_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.182	0.933	0.896	0.915
Average	0.182	0.941	0.963	0.968
Max	0.182	0.952	1.008	1.234
UL	150.000	150.000	150.000	150.000



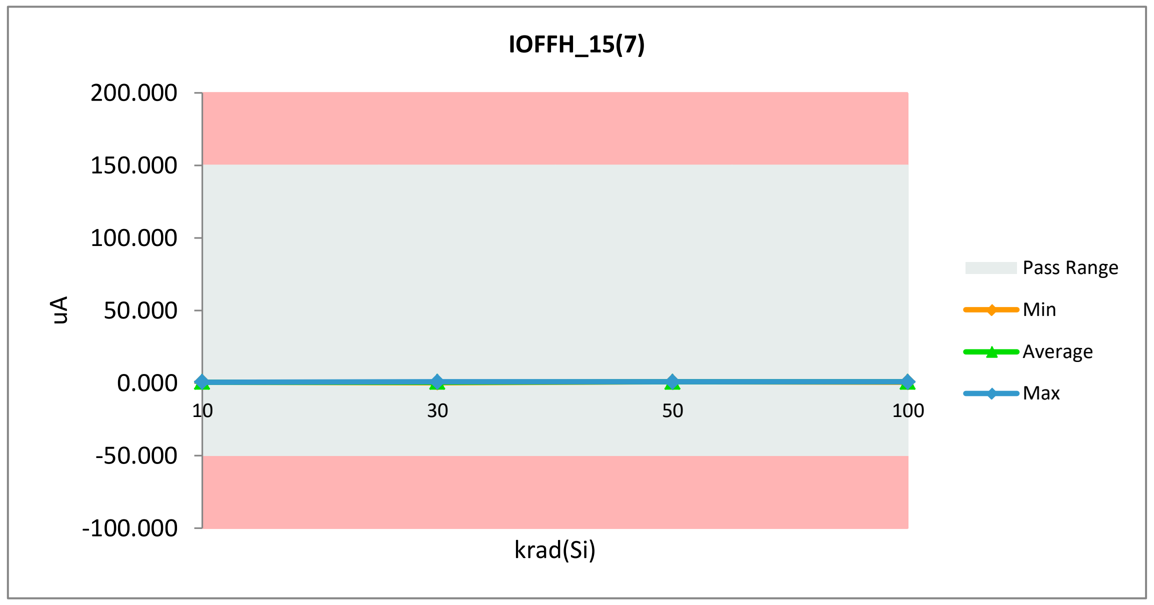
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFH_15(7)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	uA	uA	
Max Limit	150	150	
Min Limit	-50	-50	

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.017	0.846	0.171
10	7	1.017	0.846	0.171
10	8	1.017	0.846	0.171
10	9	0.716	0.846	-0.129
10	10	0.716	0.846	-0.129
30	6	0.935	0.922	0.013
30	7	0.935	0.922	0.013
30	8	0.935	0.473	0.463
30	9	0.935	0.922	0.013
30	10	1.010	0.922	0.088
50	16	0.935	0.885	0.051
50	17	0.991	0.978	0.013
50	18	1.010	0.922	0.088
50	19	0.973	0.959	0.013
50	20	0.935	0.978	-0.043
100	B043	0.991	0.774	0.217
100	B044	0.954	0.959	-0.005
100	B045	0.991	0.903	0.088
100	B046	0.917	0.941	-0.024
100	B047	1.010	0.922	0.088
100	B048	1.010	0.941	0.069
100	B049	0.935	0.941	-0.005
100	B050	0.991	0.903	0.088
100	B051	0.973	0.959	0.013
100	B052	0.954	0.941	0.013
100	B053	1.010	0.903	0.107
100	B054	0.935	0.941	-0.005
100	B055	0.935	0.922	0.013
100	B056	0.973	0.903	0.069
100	B057	0.973	0.959	0.013
100	B058	0.991	0.903	0.088
100	B059	1.010	0.903	0.107
100	B060	0.954	0.903	0.051
100	B061	1.029	0.959	0.069
100	B062	0.954	0.952	0.002
100	B063	0.954	0.941	0.013
100	B064	0.991	0.922	0.069
	Max	1.029	0.978	0.463
	Average	0.960	0.903	0.057
	Min	0.716	0.473	-0.129
	Std Dev	0.067	0.085	0.100

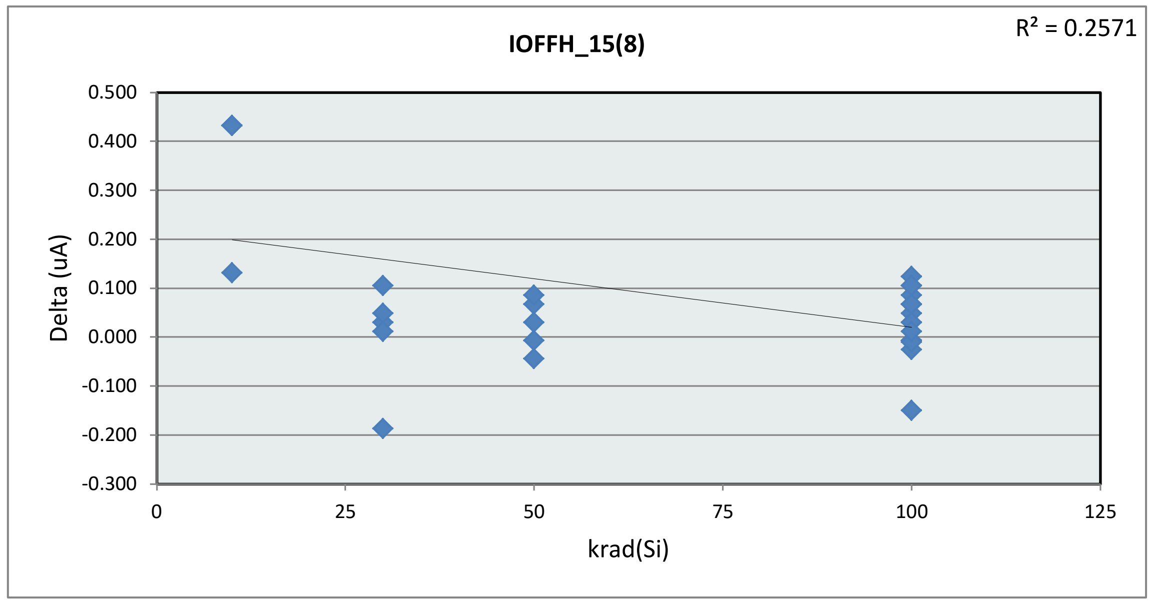


	IOFFH_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.846	0.473	0.885	0.774
Average	0.846	0.832	0.944	0.922
Max	0.846	0.922	0.978	0.959
UL	150.000	150.000	150.000	150.000

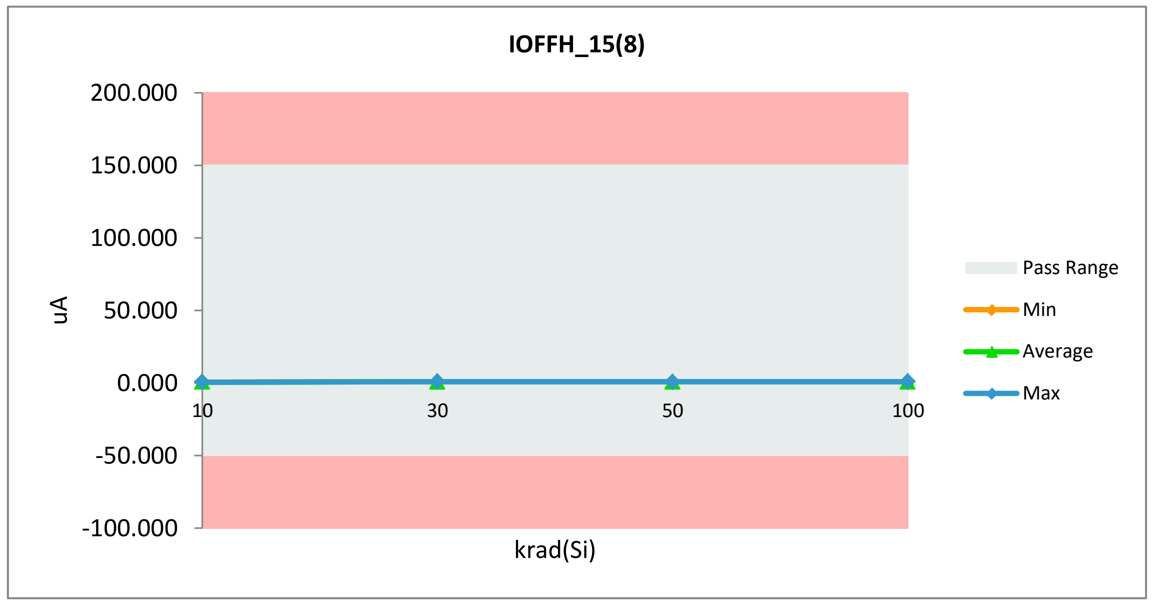


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_15(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.219	0.787	0.432
10	7	1.219	0.787	0.432
10	8	0.919	0.787	0.132
10	9	1.219	0.787	0.432
10	10	1.219	0.787	0.432
30	6	0.985	0.955	0.030
30	7	0.967	0.918	0.049
30	8	0.967	1.154	-0.187
30	9	0.948	0.937	0.012
30	10	1.060	0.955	0.105
50	16	0.967	0.900	0.067
50	17	1.023	0.993	0.030
50	18	1.023	0.937	0.086
50	19	0.985	0.993	-0.007
50	20	0.967	1.011	-0.044
100	B043	1.004	1.154	-0.150
100	B044	0.967	0.974	-0.007
100	B045	1.023	0.937	0.086
100	B046	0.967	0.974	-0.007
100	B047	1.004	0.937	0.067
100	B048	1.041	0.993	0.049
100	B049	0.967	0.974	-0.007
100	B050	1.023	0.900	0.123
100	B051	0.967	0.993	-0.026
100	B052	0.985	0.993	-0.007
100	B053	1.041	0.918	0.123
100	B054	0.967	0.974	-0.007
100	B055	0.985	0.955	0.030
100	B056	1.004	0.937	0.067
100	B057	1.023	0.955	0.067
100	B058	1.023	0.918	0.105
100	B059	1.004	0.937	0.067
100	B060	0.967	0.937	0.030
100	B061	1.060	0.955	0.105
100	B062	0.967	0.977	-0.010
100	B063	0.985	0.974	0.012
100	B064	1.041	0.937	0.105
	Max	1.219	1.154	0.432
	Average	1.019	0.943	0.076
	Min	0.919	0.787	-0.187
	Std Dev	0.078	0.082	0.142

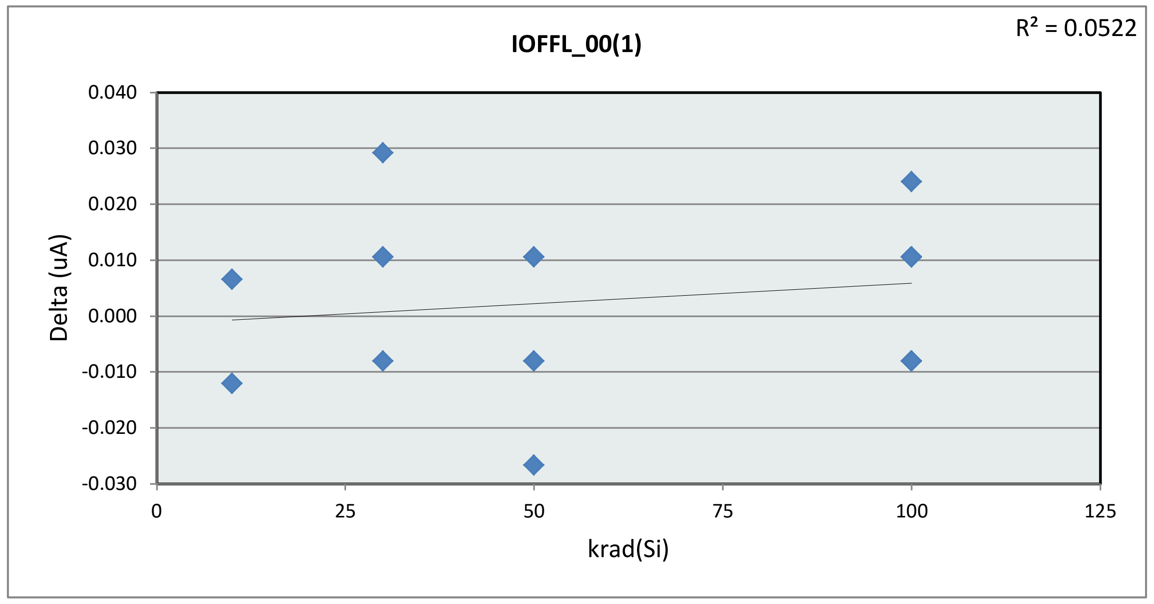


	IOFFH_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.787	0.918	0.900	0.900
Average	0.787	0.984	0.966	0.964
Max	0.787	1.154	1.011	1.154
UL	150.000	150.000	150.000	150.000

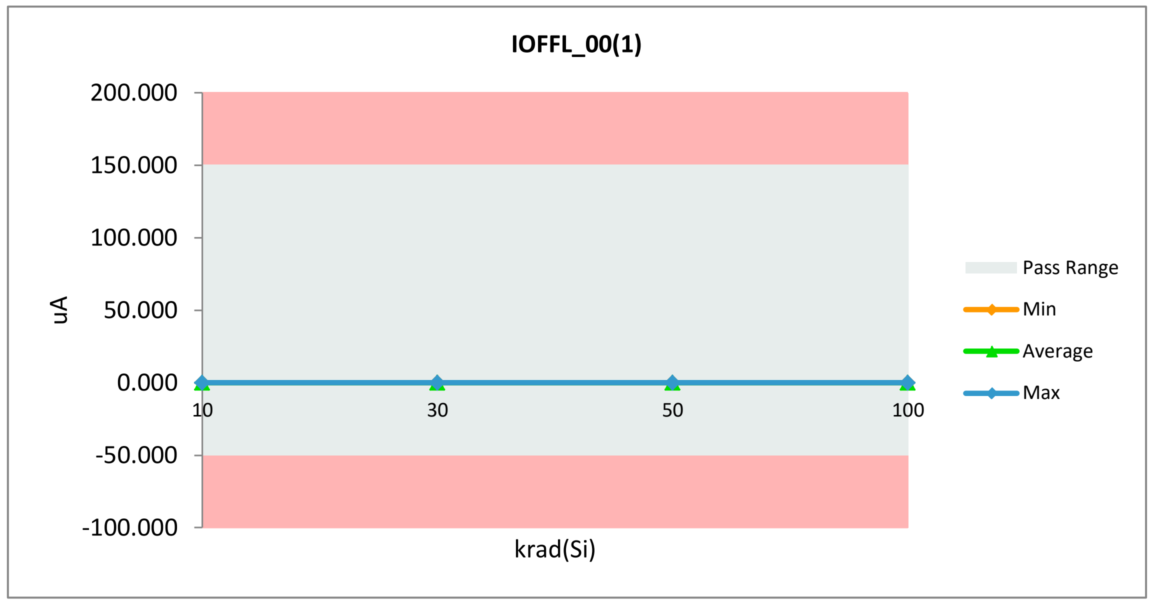


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.028	-0.016	-0.012
10	7	-0.010	-0.016	0.006
10	8	-0.028	-0.016	-0.012
10	9	-0.010	-0.016	0.006
10	10	-0.028	-0.016	-0.012
30	6	0.022	-0.007	0.029
30	7	0.003	0.011	-0.008
30	8	0.003	-0.007	0.011
30	9	0.003	-0.007	0.011
30	10	0.022	0.011	0.011
50	16	-0.015	0.011	-0.027
50	17	0.003	-0.007	0.011
50	18	-0.015	-0.007	-0.008
50	19	0.003	-0.007	0.011
50	20	0.003	0.011	-0.008
100	B043	0.003	-0.007	0.011
100	B044	0.003	-0.007	0.011
100	B045	0.022	0.011	0.011
100	B046	0.003	0.011	-0.008
100	B047	-0.015	-0.007	-0.008
100	B048	0.003	-0.007	0.011
100	B049	0.003	-0.007	0.011
100	B050	0.003	0.011	-0.008
100	B051	-0.015	-0.007	-0.008
100	B052	0.003	0.011	-0.008
100	B053	0.003	-0.007	0.011
100	B054	0.003	0.011	-0.008
100	B055	0.003	-0.007	0.011
100	B056	0.003	-0.007	0.011
100	B057	0.003	-0.007	0.011
100	B058	0.003	-0.007	0.011
100	B059	0.003	-0.007	0.011
100	B060	0.003	-0.007	0.011
100	B061	0.003	-0.007	0.011
100	B062	0.003	-0.021	0.024
100	B063	0.003	-0.007	0.011
100	B064	0.003	-0.007	0.011
	Max	0.022	0.011	0.029
	Average	0.000	-0.004	0.004
	Min	-0.028	-0.021	-0.027
	Std Dev	0.012	0.010	0.012

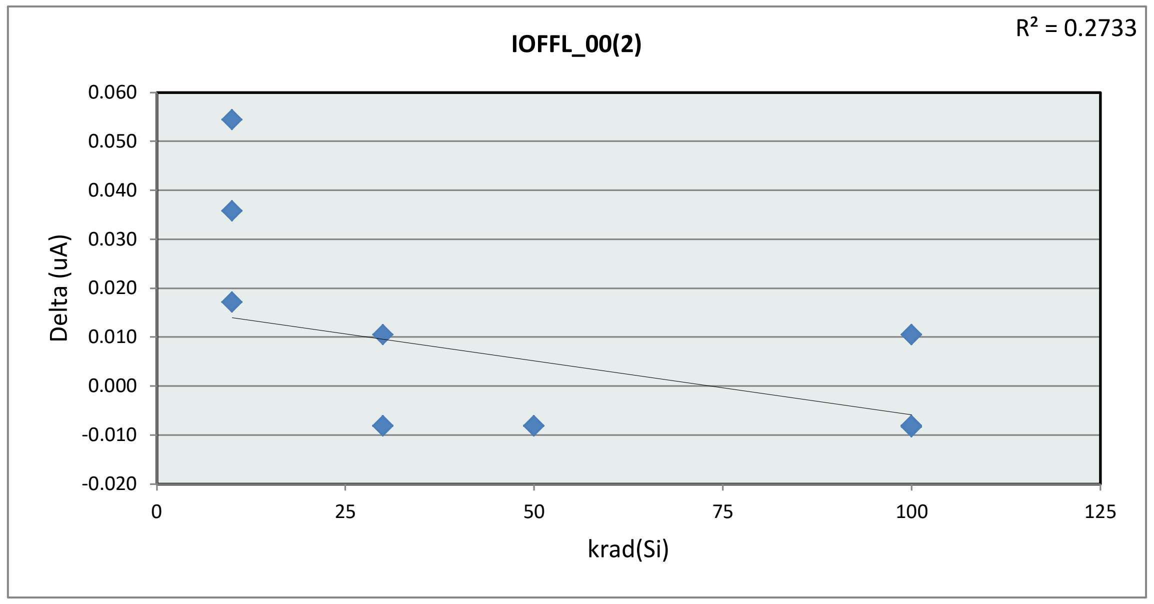


	IOFFL_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.016	-0.007	-0.007	-0.021
Average	-0.016	0.000	0.000	-0.004
Max	-0.016	0.011	0.011	0.011
UL	150.000	150.000	150.000	150.000

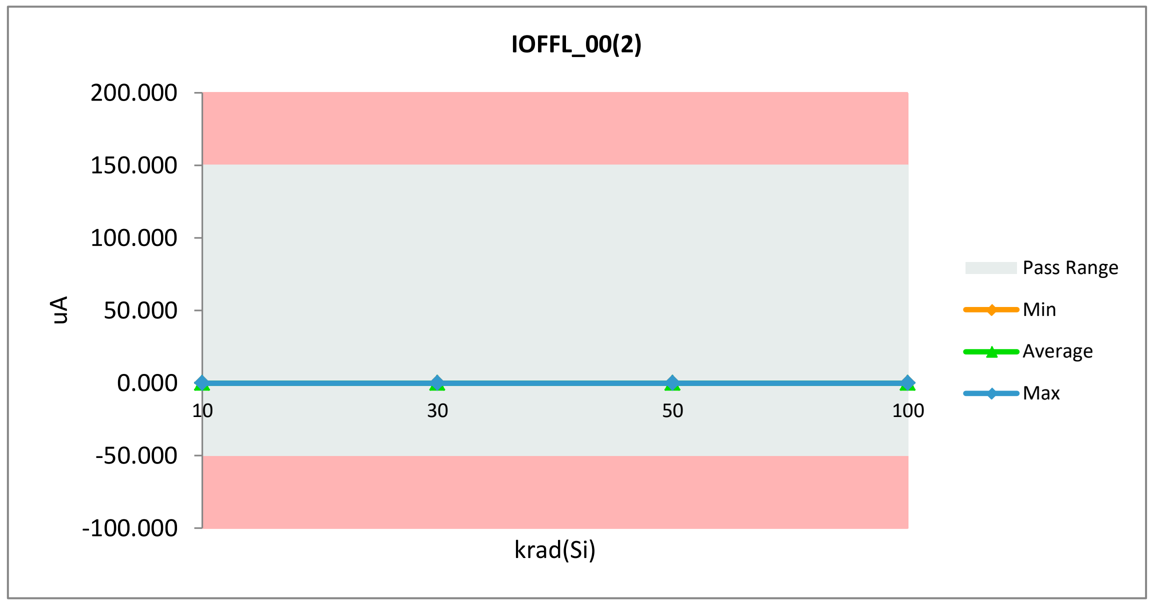


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.010	-0.027	0.017
10	7	-0.010	-0.046	0.036
10	8	0.008	-0.046	0.054
10	9	-0.010	-0.027	0.017
10	10	-0.010	-0.046	0.036
30	6	-0.005	0.003	-0.008
30	7	-0.005	0.003	-0.008
30	8	-0.005	0.003	-0.008
30	9	-0.005	-0.016	0.011
30	10	-0.005	0.003	-0.008
50	16	-0.005	0.003	-0.008
50	17	-0.005	0.003	-0.008
50	18	-0.005	0.003	-0.008
50	19	-0.005	0.003	-0.008
50	20	-0.005	0.003	-0.008
100	B043	-0.005	0.003	-0.008
100	B044	-0.005	0.003	-0.008
100	B045	0.013	0.003	0.011
100	B046	-0.005	0.003	-0.008
100	B047	-0.005	0.003	-0.008
100	B048	-0.005	0.003	-0.008
100	B049	-0.005	0.003	-0.008
100	B050	-0.005	0.003	-0.008
100	B051	-0.005	0.003	-0.008
100	B052	-0.005	0.003	-0.008
100	B053	-0.005	0.003	-0.008
100	B054	-0.005	0.003	-0.008
100	B055	-0.005	0.003	-0.008
100	B056	-0.005	-0.016	0.011
100	B057	-0.005	0.003	-0.008
100	B058	0.013	0.003	0.011
100	B059	0.013	0.003	0.011
100	B060	-0.005	0.003	-0.008
100	B061	-0.005	0.003	-0.008
100	B062	-0.005	0.003	-0.008
100	B063	-0.005	0.003	-0.008
100	B064	0.013	0.003	0.011
	Max	0.013	0.003	0.054
	Average	-0.004	-0.004	0.000
	Min	-0.010	-0.046	-0.008
	Std Dev	0.007	0.015	0.015

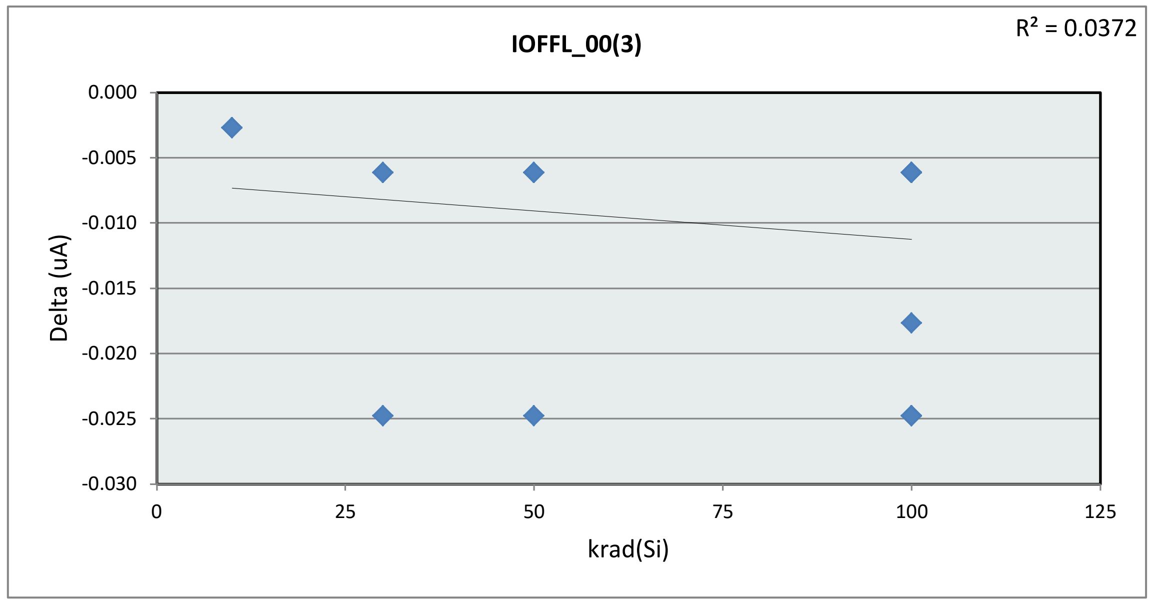


	IOFFL_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.046	-0.016	0.003	-0.016
Average	-0.039	-0.001	0.003	0.002
Max	-0.027	0.003	0.003	0.003
UL	150.000	150.000	150.000	150.000

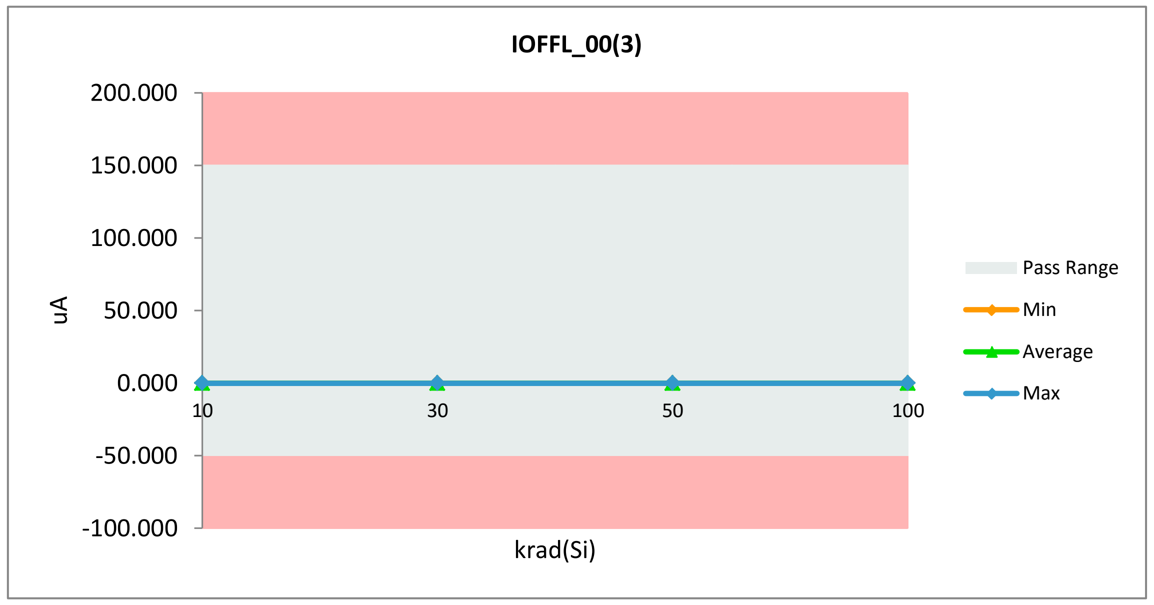


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.002	0.001	-0.003
10	7	-0.002	0.001	-0.003
10	8	-0.002	0.001	-0.003
10	9	-0.002	0.001	-0.003
10	10	-0.002	0.001	-0.003
30	6	-0.016	0.009	-0.025
30	7	-0.016	-0.010	-0.006
30	8	-0.035	-0.010	-0.025
30	9	-0.016	-0.010	-0.006
30	10	-0.016	-0.010	-0.006
50	16	-0.016	-0.010	-0.006
50	17	-0.016	0.009	-0.025
50	18	-0.016	-0.010	-0.006
50	19	-0.016	-0.010	-0.006
50	20	-0.016	-0.010	-0.006
100	B043	-0.016	-0.010	-0.006
100	B044	-0.016	0.009	-0.025
100	B045	-0.016	-0.010	-0.006
100	B046	-0.016	0.009	-0.025
100	B047	-0.016	-0.010	-0.006
100	B048	-0.016	-0.010	-0.006
100	B049	-0.016	-0.010	-0.006
100	B050	-0.016	-0.010	-0.006
100	B051	-0.016	0.009	-0.025
100	B052	-0.016	-0.010	-0.006
100	B053	-0.016	-0.010	-0.006
100	B054	-0.016	0.009	-0.025
100	B055	-0.016	-0.010	-0.006
100	B056	-0.016	-0.010	-0.006
100	B057	-0.035	-0.010	-0.025
100	B058	-0.016	-0.010	-0.006
100	B059	-0.016	-0.010	-0.006
100	B060	-0.016	-0.010	-0.006
100	B061	-0.016	-0.010	-0.006
100	B062	-0.016	0.002	-0.018
100	B063	-0.016	-0.010	-0.006
100	B064	-0.016	-0.010	-0.006
	Max	-0.002	0.009	-0.003
	Average	-0.015	-0.005	-0.010
	Min	-0.035	-0.010	-0.025
	Std Dev	0.007	0.007	0.008

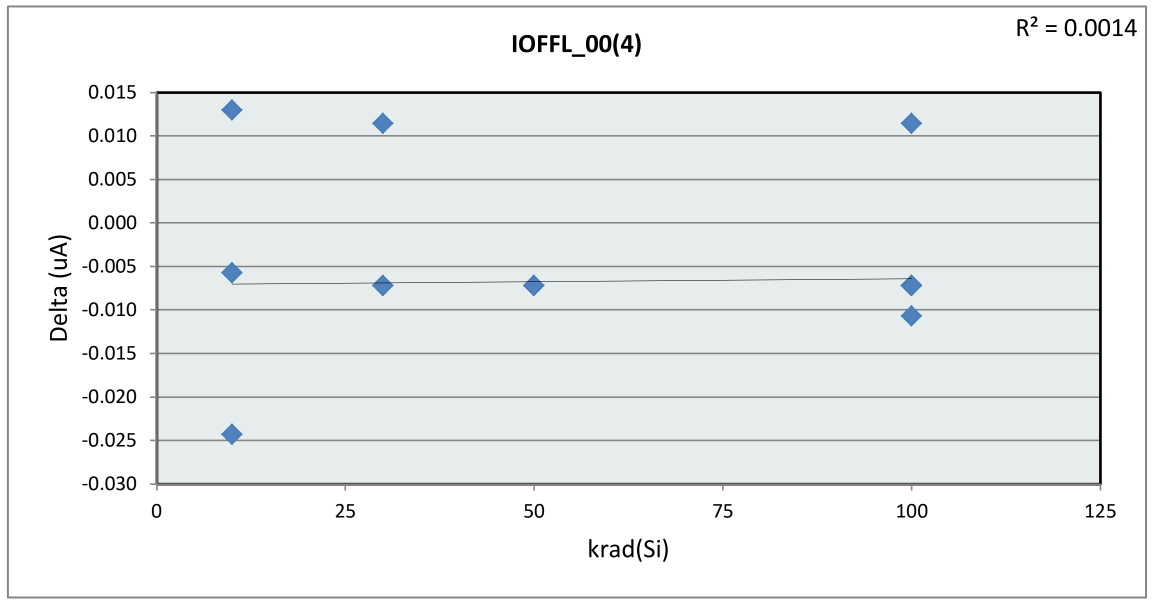


	IOFFL_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.001	-0.010	-0.010	-0.010
Average	0.001	-0.006	-0.006	-0.006
Max	0.001	0.009	0.009	0.009
UL	150.000	150.000	150.000	150.000

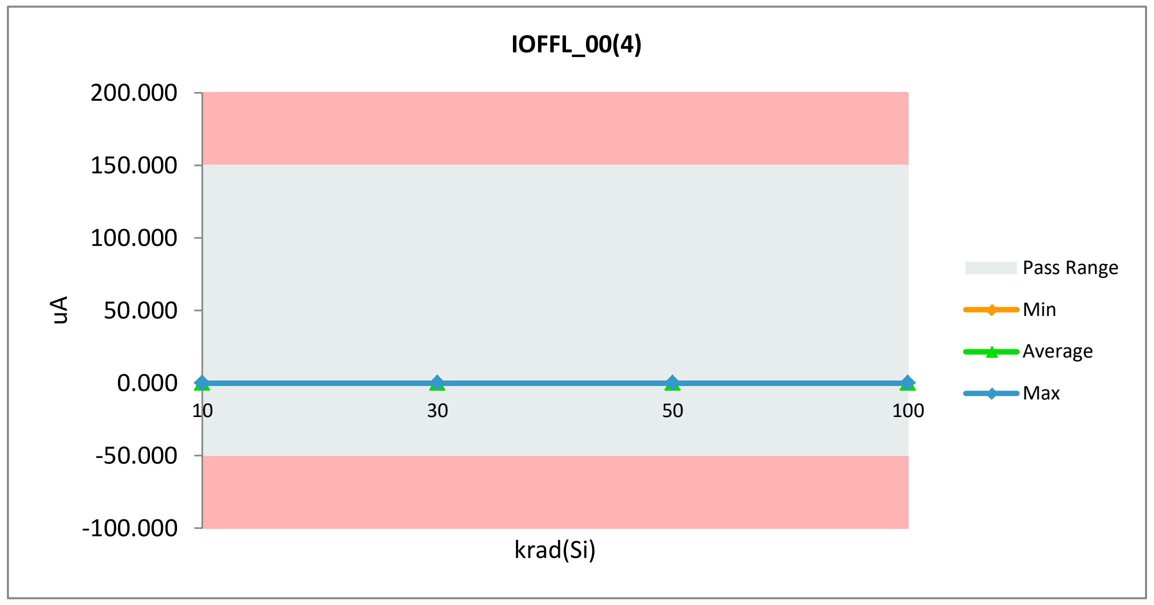


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.026	-0.001	-0.024
10	7	-0.026	-0.001	-0.024
10	8	-0.007	-0.001	-0.006
10	9	-0.007	-0.020	0.013
10	10	-0.007	-0.001	-0.006
30	6	-0.019	-0.031	0.011
30	7	-0.019	-0.012	-0.007
30	8	-0.019	-0.012	-0.007
30	9	-0.019	-0.012	-0.007
30	10	-0.019	-0.012	-0.007
50	16	-0.019	-0.012	-0.007
50	17	-0.019	-0.012	-0.007
50	18	-0.019	-0.012	-0.007
50	19	-0.019	-0.012	-0.007
50	20	-0.019	-0.012	-0.007
100	B043	-0.019	-0.012	-0.007
100	B044	-0.019	-0.012	-0.007
100	B045	-0.019	-0.012	-0.007
100	B046	-0.019	-0.012	-0.007
100	B047	-0.019	-0.012	-0.007
100	B048	-0.019	-0.012	-0.007
100	B049	-0.019	-0.012	-0.007
100	B050	-0.019	-0.031	0.011
100	B051	-0.019	-0.012	-0.007
100	B052	-0.019	-0.012	-0.007
100	B053	-0.019	-0.012	-0.007
100	B054	-0.019	-0.012	-0.007
100	B055	-0.019	-0.012	-0.007
100	B056	-0.019	-0.012	-0.007
100	B057	-0.019	-0.012	-0.007
100	B058	-0.019	-0.012	-0.007
100	B059	-0.019	-0.012	-0.007
100	B060	-0.019	-0.012	-0.007
100	B061	-0.019	-0.012	-0.007
100	B062	-0.019	-0.008	-0.011
100	B063	-0.019	-0.012	-0.007
100	B064	-0.019	-0.012	-0.007
	Max	-0.007	-0.001	0.013
	Average	-0.019	-0.012	-0.007
	Min	-0.026	-0.031	-0.024
	Std Dev	0.004	0.006	0.007

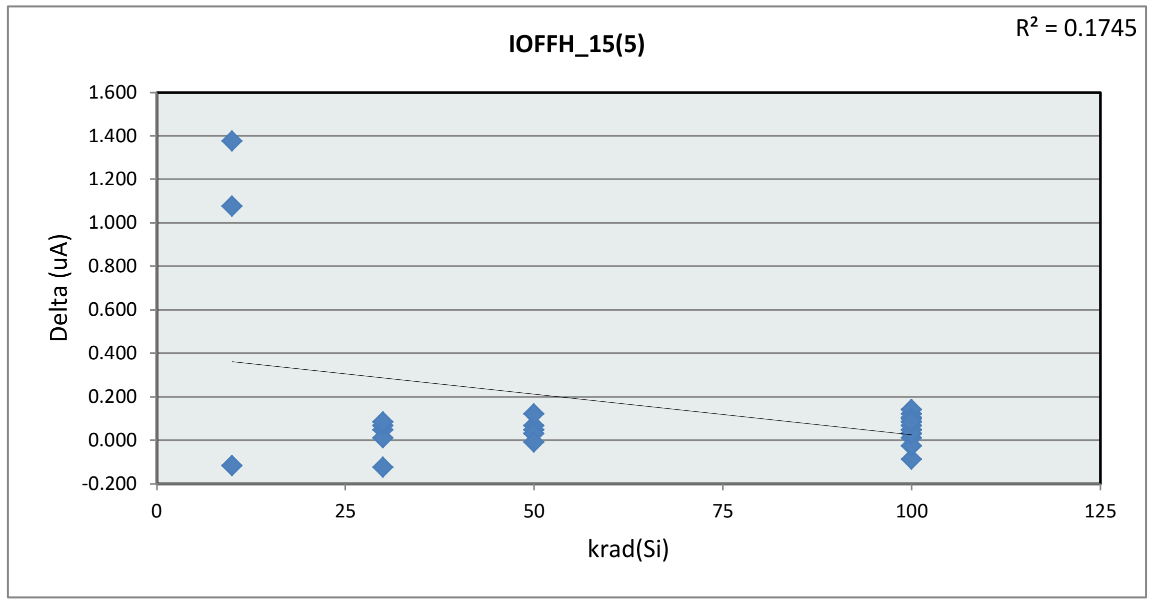


	IOFFL_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.020	-0.031	-0.012	-0.031
Average	-0.005	-0.016	-0.012	-0.013
Max	-0.001	-0.012	-0.012	-0.008
UL	150.000	150.000	150.000	150.000

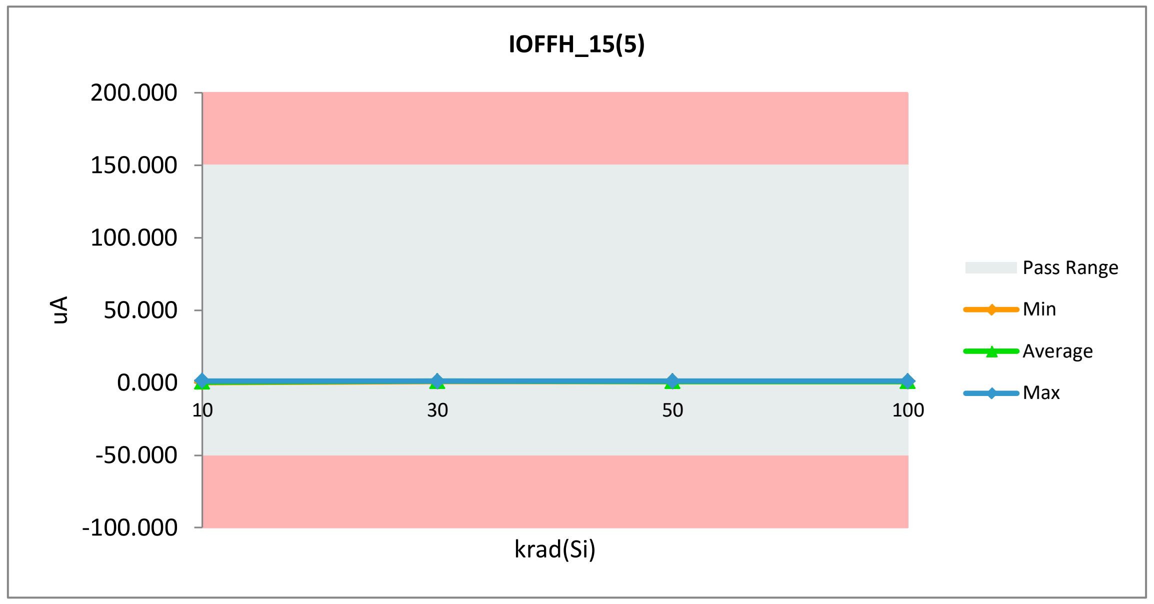


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_15(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.146	0.071	1.075
10	7	1.146	1.262	-0.116
10	8	1.446	0.071	1.375
10	9	1.146	0.071	1.075
10	10	1.146	1.262	-0.116
30	6	1.008	0.960	0.048
30	7	0.971	0.960	0.010
30	8	0.989	1.113	-0.124
30	9	1.008	0.942	0.066
30	10	1.026	0.942	0.085
50	16	0.971	0.904	0.066
50	17	1.045	0.997	0.048
50	18	1.064	0.942	0.122
50	19	1.026	0.997	0.029
50	20	1.008	1.016	-0.008
100	B043	1.026	1.113	-0.087
100	B044	1.026	0.997	0.029
100	B045	1.026	0.923	0.103
100	B046	0.971	0.942	0.029
100	B047	1.008	0.960	0.048
100	B048	1.026	0.960	0.066
100	B049	0.971	0.997	-0.027
100	B050	1.045	0.904	0.141
100	B051	1.026	0.960	0.066
100	B052	1.008	0.960	0.048
100	B053	1.045	0.923	0.122
100	B054	0.989	0.979	0.010
100	B055	0.915	0.942	-0.027
100	B056	0.989	0.942	0.048
100	B057	1.026	0.979	0.048
100	B058	1.026	0.942	0.085
100	B059	1.026	0.942	0.085
100	B060	1.008	0.923	0.085
100	B061	1.101	0.960	0.141
100	B062	1.026	0.928	0.098
100	B063	0.989	0.960	0.029
100	B064	1.026	0.942	0.085
	Max	1.446	1.262	1.375
	Average	1.039	0.908	0.131
	Min	0.915	0.071	-0.124
	Std Dev	0.086	0.265	0.324

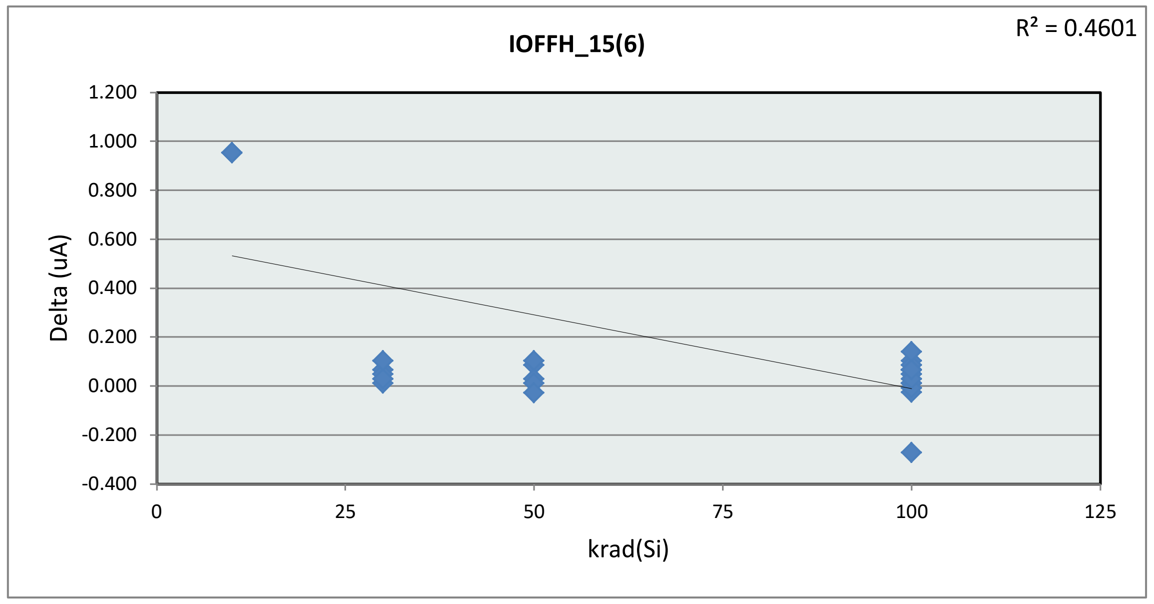


	IOFFH_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.071	0.942	0.904	0.904
Average	0.547	0.983	0.971	0.958
Max	1.262	1.113	1.016	1.113
UL	150.000	150.000	150.000	150.000

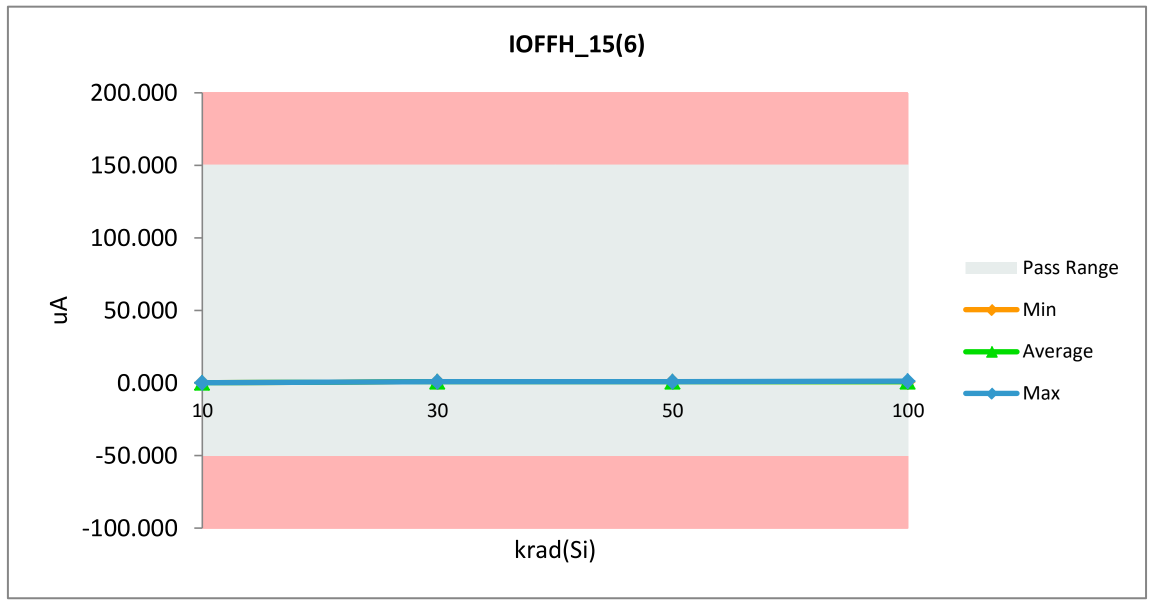


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_15(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.135	0.182	0.953
10	7	1.135	0.182	0.953
10	8	1.135	0.182	0.953
10	9	1.135	0.182	0.953
10	10	1.135	0.182	0.953
30	6	1.000	0.933	0.067
30	7	0.962	0.952	0.011
30	8	0.981	0.934	0.048
30	9	0.981	0.952	0.029
30	10	1.037	0.933	0.104
50	16	0.981	0.896	0.085
50	17	1.018	0.989	0.029
50	18	1.037	0.933	0.104
50	19	1.000	0.989	0.011
50	20	0.981	1.008	-0.027
100	B043	0.962	1.234	-0.272
100	B044	1.000	0.989	0.011
100	B045	1.000	0.933	0.067
100	B046	0.962	0.952	0.011
100	B047	1.037	0.970	0.067
100	B048	1.000	0.952	0.048
100	B049	1.000	0.989	0.011
100	B050	1.018	0.915	0.104
100	B051	0.981	0.989	-0.008
100	B052	0.981	0.970	0.011
100	B053	1.018	0.933	0.085
100	B054	0.962	0.989	-0.027
100	B055	1.000	0.933	0.067
100	B056	0.981	0.933	0.048
100	B057	1.000	1.008	-0.008
100	B058	1.000	0.933	0.067
100	B059	1.037	0.952	0.085
100	B060	0.981	0.915	0.067
100	B061	1.093	0.952	0.141
100	B062	1.000	0.933	0.066
100	B063	1.000	0.970	0.029
100	B064	1.018	0.952	0.067
	Max	1.135	1.234	0.953
	Average	1.018	0.858	0.161
	Min	0.962	0.182	-0.272
	Std Dev	0.053	0.276	0.324



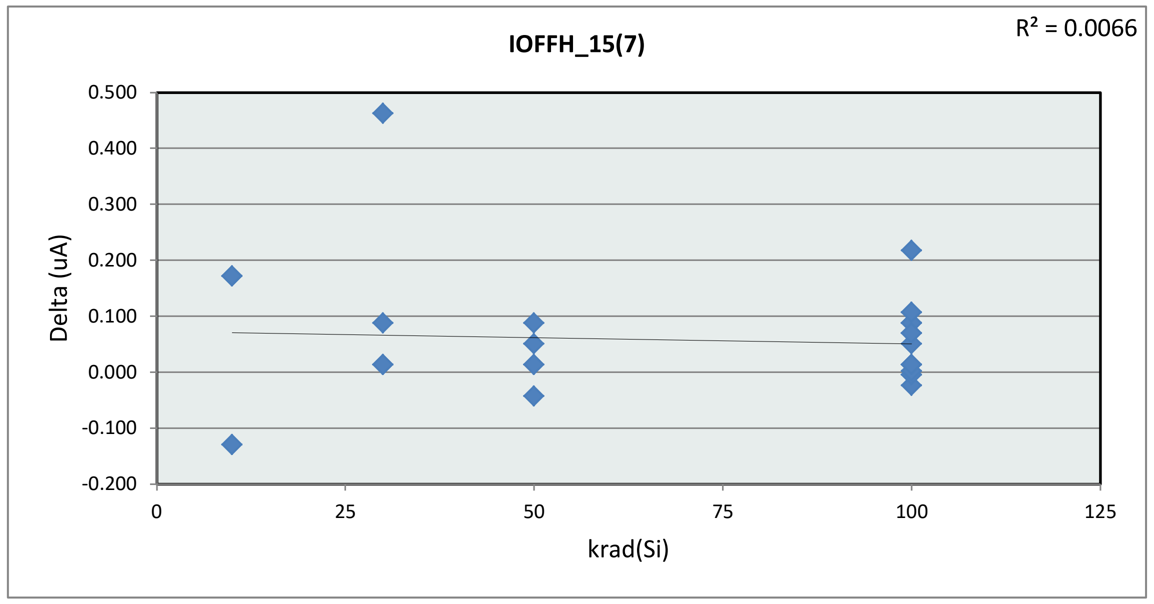
	IOFFH_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.182	0.933	0.896	0.915
Average	0.182	0.941	0.963	0.968
Max	0.182	0.952	1.008	1.234
UL	150.000	150.000	150.000	150.000



HDR UnBiased TID Report
SN55LVCP22A-SP

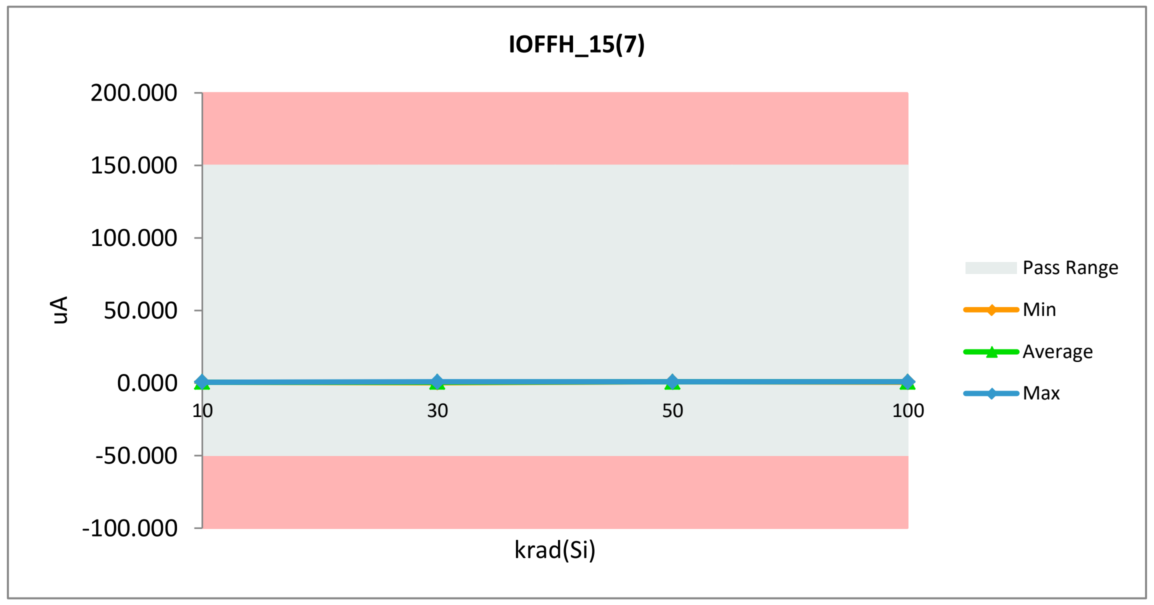
	IOFFH_15(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.017	0.846	0.171
10	7	1.017	0.846	0.171
10	8	1.017	0.846	0.171
10	9	0.716	0.846	-0.129
10	10	0.716	0.846	-0.129
30	6	0.935	0.922	0.013
30	7	0.935	0.922	0.013
30	8	0.935	0.473	0.463
30	9	0.935	0.922	0.013
30	10	1.010	0.922	0.088
50	16	0.935	0.885	0.051
50	17	0.991	0.978	0.013
50	18	1.010	0.922	0.088
50	19	0.973	0.959	0.013
50	20	0.935	0.978	-0.043
100	B043	0.991	0.774	0.217
100	B044	0.954	0.959	-0.005
100	B045	0.991	0.903	0.088
100	B046	0.917	0.941	-0.024
100	B047	1.010	0.922	0.088
100	B048	1.010	0.941	0.069
100	B049	0.935	0.941	-0.005
100	B050	0.991	0.903	0.088
100	B051	0.973	0.959	0.013
100	B052	0.954	0.941	0.013
100	B053	1.010	0.903	0.107
100	B054	0.935	0.941	-0.005
100	B055	0.935	0.922	0.013
100	B056	0.973	0.903	0.069
100	B057	0.973	0.959	0.013
100	B058	0.991	0.903	0.088
100	B059	1.010	0.903	0.107
100	B060	0.954	0.903	0.051
100	B061	1.029	0.959	0.069
100	B062	0.954	0.952	0.002
100	B063	0.954	0.941	0.013
100	B064	0.991	0.922	0.069
	Max	1.029	0.978	0.463
	Average	0.960	0.903	0.057
	Min	0.716	0.473	-0.129
	Std Dev	0.067	0.085	0.100



	IOFFH_15(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	uA
Min Limit	-50	uA

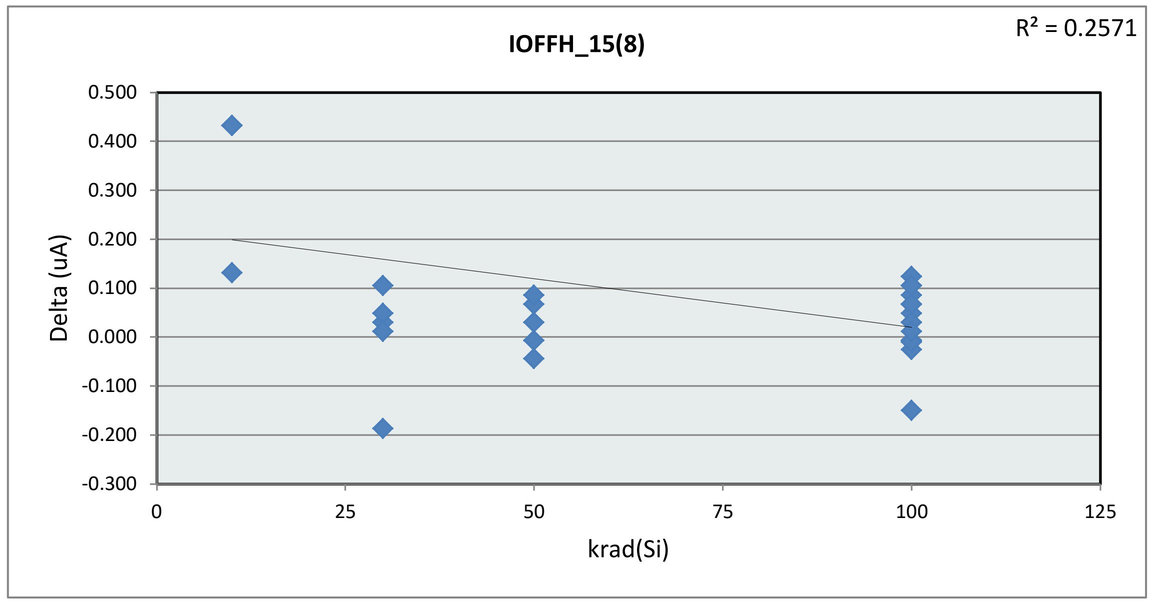
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.846	0.473	0.885	0.774
Average	0.846	0.832	0.944	0.922
Max	0.846	0.922	0.978	0.959
UL	150.000	150.000	150.000	150.000



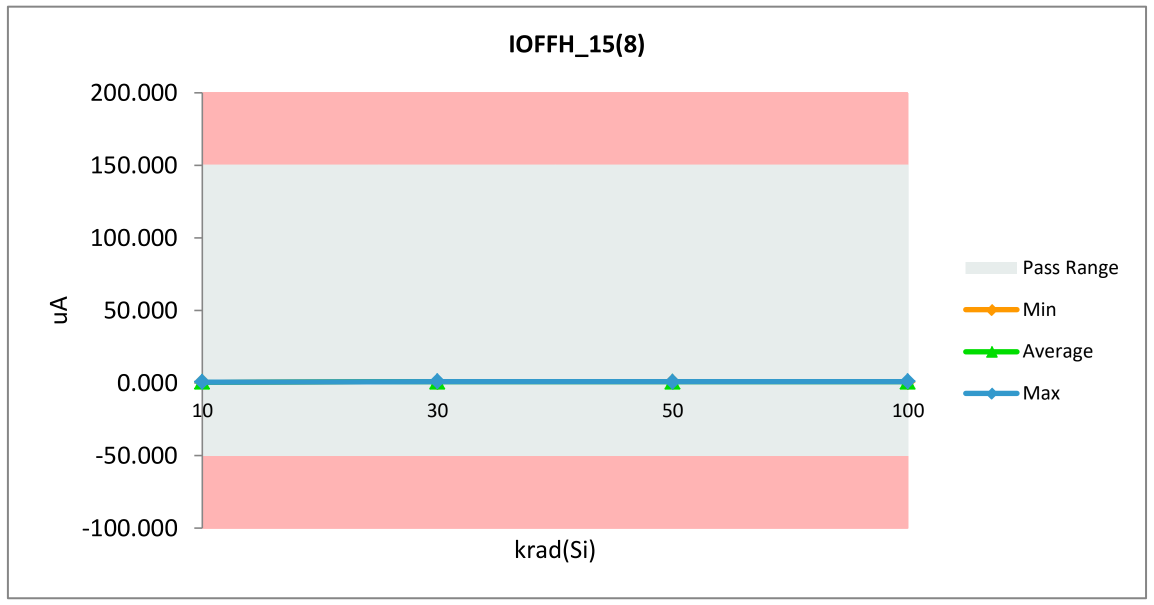
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFH_15(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.219	0.787	0.432
10	7	1.219	0.787	0.432
10	8	0.919	0.787	0.132
10	9	1.219	0.787	0.432
10	10	1.219	0.787	0.432
30	6	0.985	0.955	0.030
30	7	0.967	0.918	0.049
30	8	0.967	1.154	-0.187
30	9	0.948	0.937	0.012
30	10	1.060	0.955	0.105
50	16	0.967	0.900	0.067
50	17	1.023	0.993	0.030
50	18	1.023	0.937	0.086
50	19	0.985	0.993	-0.007
50	20	0.967	1.011	-0.044
100	B043	1.004	1.154	-0.150
100	B044	0.967	0.974	-0.007
100	B045	1.023	0.937	0.086
100	B046	0.967	0.974	-0.007
100	B047	1.004	0.937	0.067
100	B048	1.041	0.993	0.049
100	B049	0.967	0.974	-0.007
100	B050	1.023	0.900	0.123
100	B051	0.967	0.993	-0.026
100	B052	0.985	0.993	-0.007
100	B053	1.041	0.918	0.123
100	B054	0.967	0.974	-0.007
100	B055	0.985	0.955	0.030
100	B056	1.004	0.937	0.067
100	B057	1.023	0.955	0.067
100	B058	1.023	0.918	0.105
100	B059	1.004	0.937	0.067
100	B060	0.967	0.937	0.030
100	B061	1.060	0.955	0.105
100	B062	0.967	0.977	-0.010
100	B063	0.985	0.974	0.012
100	B064	1.041	0.937	0.105
	Max	1.219	1.154	0.432
	Average	1.019	0.943	0.076
	Min	0.919	0.787	-0.187
	Std Dev	0.078	0.082	0.142



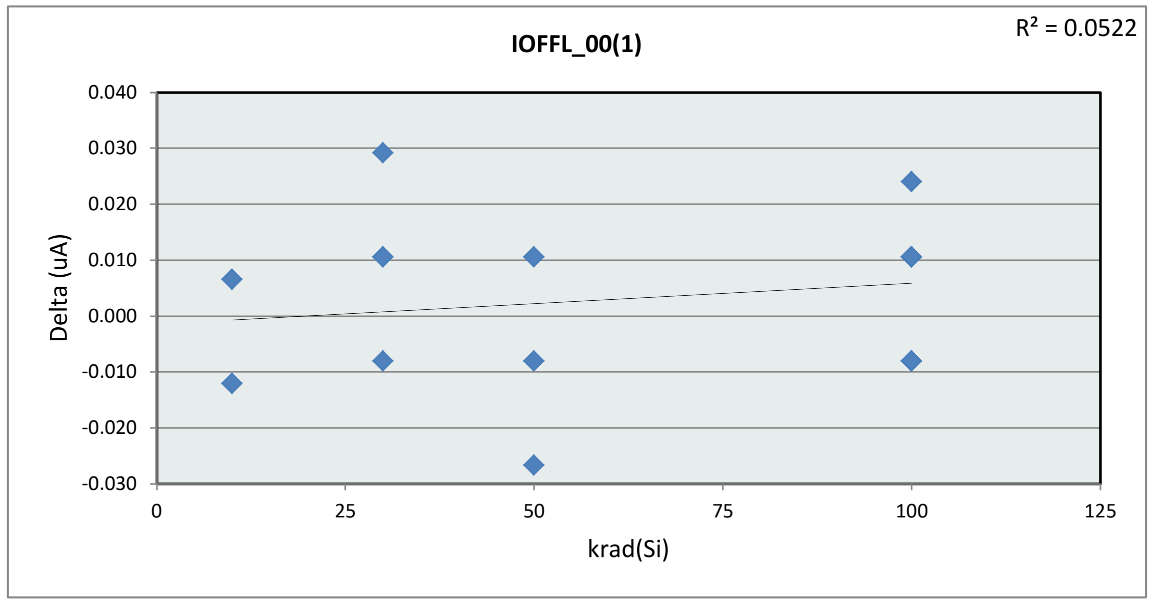
	IOFFH_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.787	0.918	0.900	0.900
Average	0.787	0.984	0.966	0.964
Max	0.787	1.154	1.011	1.154
UL	150.000	150.000	150.000	150.000



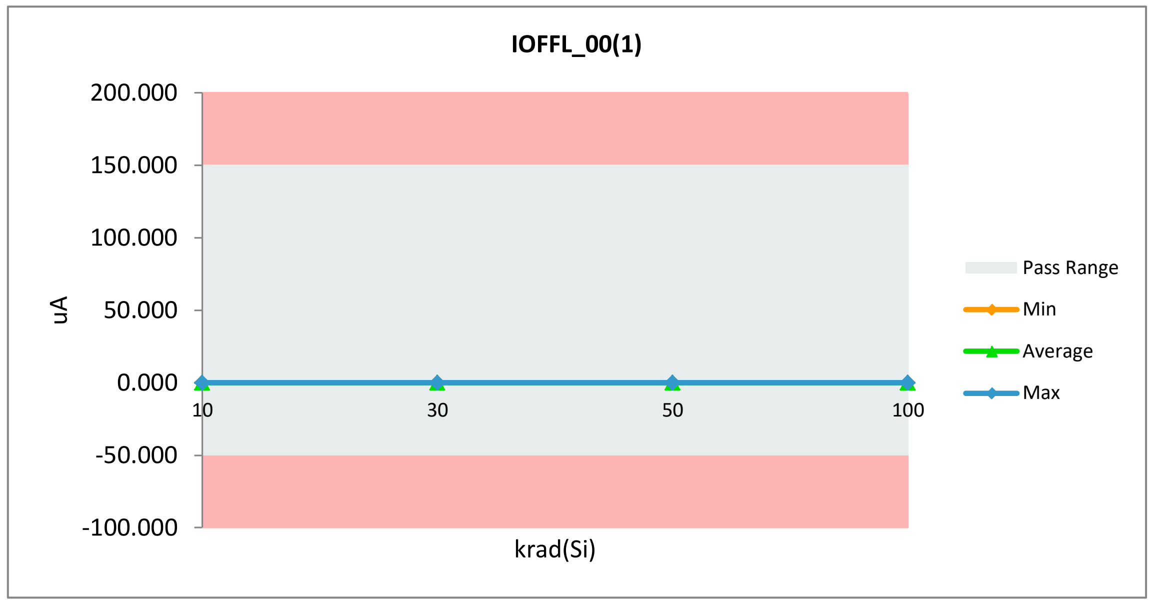
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFL_00(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.028	-0.016	-0.012
10	7	-0.010	-0.016	0.006
10	8	-0.028	-0.016	-0.012
10	9	-0.010	-0.016	0.006
10	10	-0.028	-0.016	-0.012
30	6	0.022	-0.007	0.029
30	7	0.003	0.011	-0.008
30	8	0.003	-0.007	0.011
30	9	0.003	-0.007	0.011
30	10	0.022	0.011	0.011
50	16	-0.015	0.011	-0.027
50	17	0.003	-0.007	0.011
50	18	-0.015	-0.007	-0.008
50	19	0.003	-0.007	0.011
50	20	0.003	0.011	-0.008
100	B043	0.003	-0.007	0.011
100	B044	0.003	-0.007	0.011
100	B045	0.022	0.011	0.011
100	B046	0.003	0.011	-0.008
100	B047	-0.015	-0.007	-0.008
100	B048	0.003	-0.007	0.011
100	B049	0.003	-0.007	0.011
100	B050	0.003	0.011	-0.008
100	B051	-0.015	-0.007	-0.008
100	B052	0.003	0.011	-0.008
100	B053	0.003	-0.007	0.011
100	B054	0.003	0.011	-0.008
100	B055	0.003	-0.007	0.011
100	B056	0.003	-0.007	0.011
100	B057	0.003	-0.007	0.011
100	B058	0.003	-0.007	0.011
100	B059	0.003	-0.007	0.011
100	B060	0.003	-0.007	0.011
100	B061	0.003	-0.007	0.011
100	B062	0.003	-0.021	0.024
100	B063	0.003	-0.007	0.011
100	B064	0.003	-0.007	0.011
	Max	0.022	0.011	0.029
	Average	0.000	-0.004	0.004
	Min	-0.028	-0.021	-0.027
	Std Dev	0.012	0.010	0.012

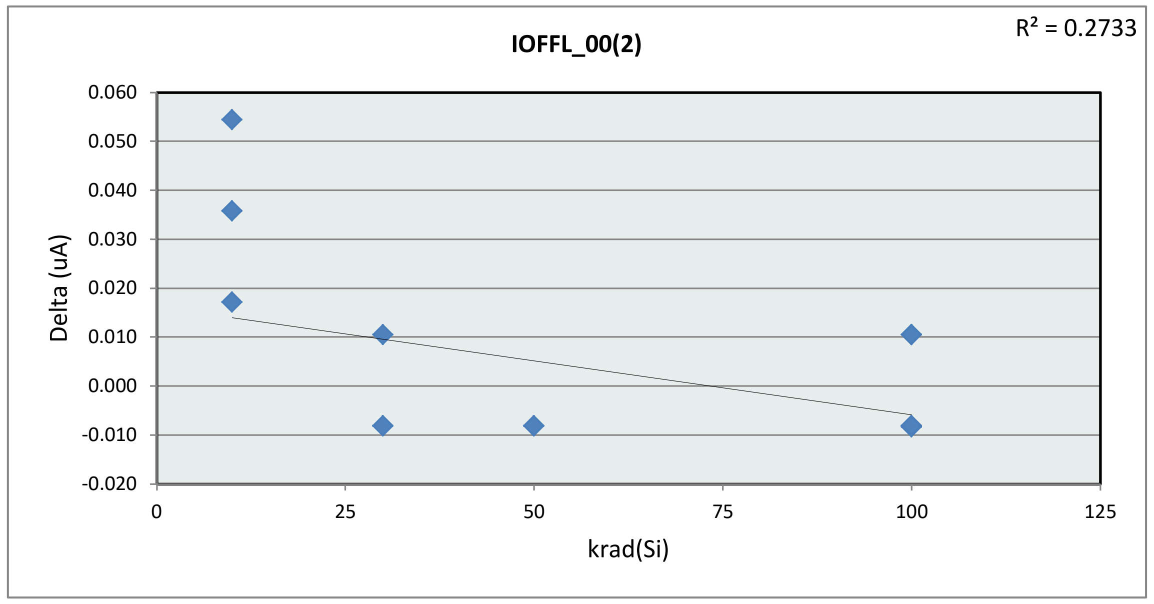


	IOFFL_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.016	-0.007	-0.007	-0.021
Average	-0.016	0.000	0.000	-0.004
Max	-0.016	0.011	0.011	0.011
UL	150.000	150.000	150.000	150.000

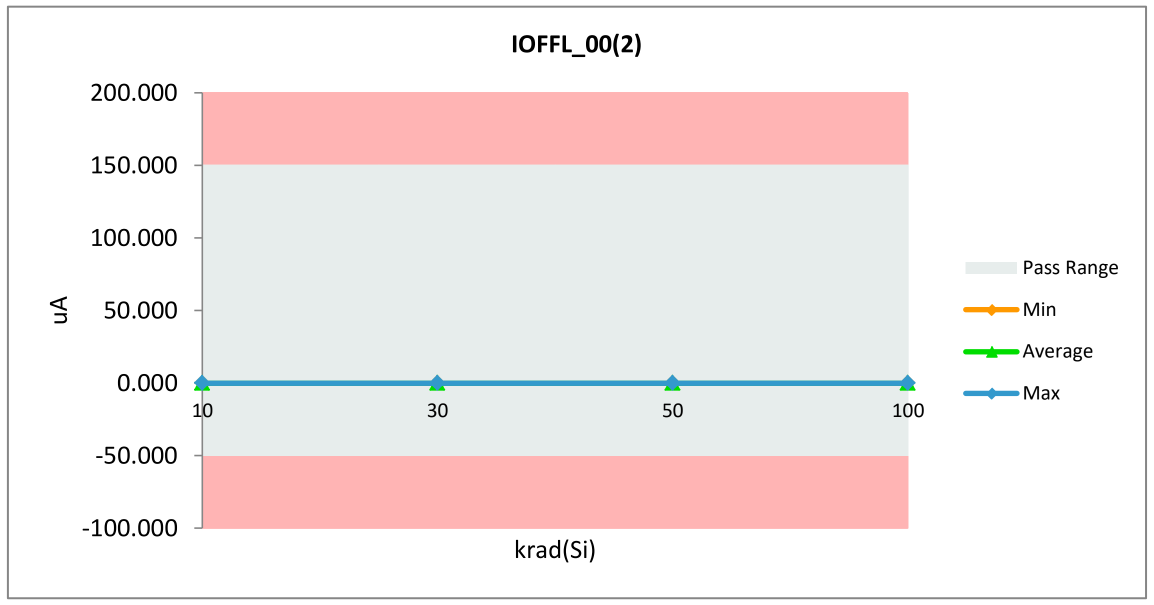


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.010	-0.027	0.017
10	7	-0.010	-0.046	0.036
10	8	0.008	-0.046	0.054
10	9	-0.010	-0.027	0.017
10	10	-0.010	-0.046	0.036
30	6	-0.005	0.003	-0.008
30	7	-0.005	0.003	-0.008
30	8	-0.005	0.003	-0.008
30	9	-0.005	-0.016	0.011
30	10	-0.005	0.003	-0.008
50	16	-0.005	0.003	-0.008
50	17	-0.005	0.003	-0.008
50	18	-0.005	0.003	-0.008
50	19	-0.005	0.003	-0.008
50	20	-0.005	0.003	-0.008
100	B043	-0.005	0.003	-0.008
100	B044	-0.005	0.003	-0.008
100	B045	0.013	0.003	0.011
100	B046	-0.005	0.003	-0.008
100	B047	-0.005	0.003	-0.008
100	B048	-0.005	0.003	-0.008
100	B049	-0.005	0.003	-0.008
100	B050	-0.005	0.003	-0.008
100	B051	-0.005	0.003	-0.008
100	B052	-0.005	0.003	-0.008
100	B053	-0.005	0.003	-0.008
100	B054	-0.005	0.003	-0.008
100	B055	-0.005	0.003	-0.008
100	B056	-0.005	-0.016	0.011
100	B057	-0.005	0.003	-0.008
100	B058	0.013	0.003	0.011
100	B059	0.013	0.003	0.011
100	B060	-0.005	0.003	-0.008
100	B061	-0.005	0.003	-0.008
100	B062	-0.005	0.003	-0.008
100	B063	-0.005	0.003	-0.008
100	B064	0.013	0.003	0.011
	Max	0.013	0.003	0.054
	Average	-0.004	-0.004	0.000
	Min	-0.010	-0.046	-0.008
	Std Dev	0.007	0.015	0.015

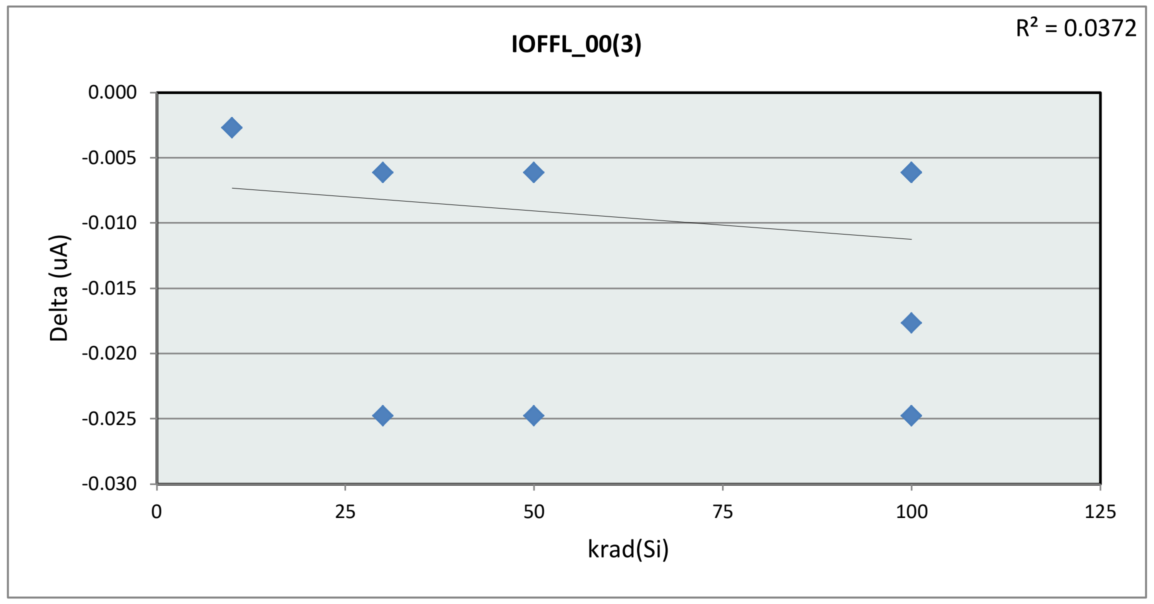


	IOFFL_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.046	-0.016	0.003	-0.016
Average	-0.039	-0.001	0.003	0.002
Max	-0.027	0.003	0.003	0.003
UL	150.000	150.000	150.000	150.000

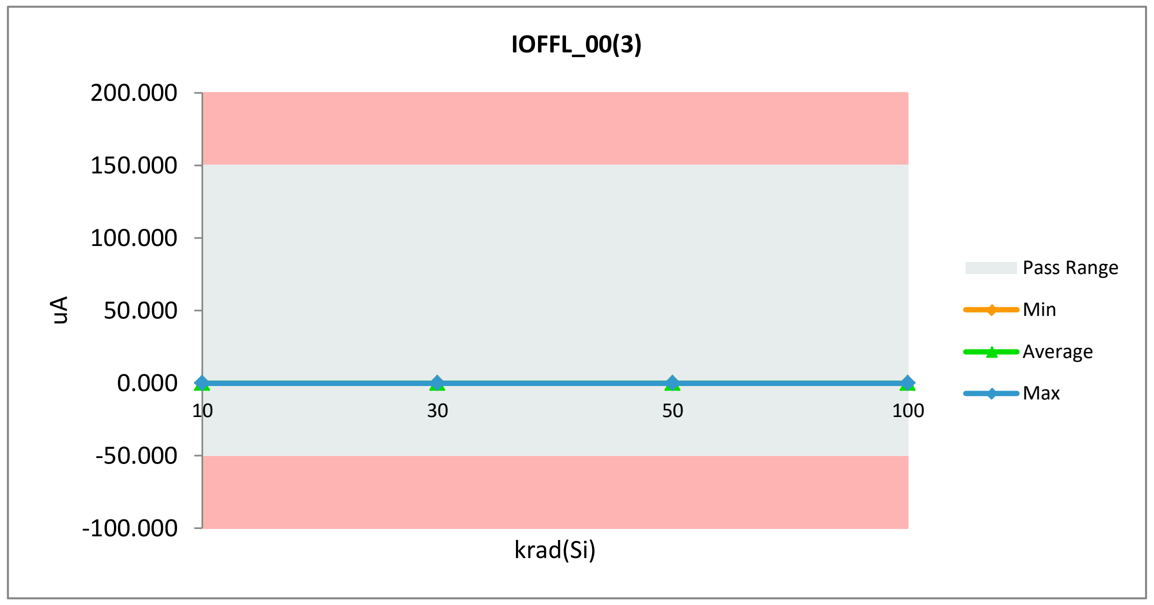


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.002	0.001	-0.003
10	7	-0.002	0.001	-0.003
10	8	-0.002	0.001	-0.003
10	9	-0.002	0.001	-0.003
10	10	-0.002	0.001	-0.003
30	6	-0.016	0.009	-0.025
30	7	-0.016	-0.010	-0.006
30	8	-0.035	-0.010	-0.025
30	9	-0.016	-0.010	-0.006
30	10	-0.016	-0.010	-0.006
50	16	-0.016	-0.010	-0.006
50	17	-0.016	0.009	-0.025
50	18	-0.016	-0.010	-0.006
50	19	-0.016	-0.010	-0.006
50	20	-0.016	-0.010	-0.006
100	B043	-0.016	-0.010	-0.006
100	B044	-0.016	0.009	-0.025
100	B045	-0.016	-0.010	-0.006
100	B046	-0.016	0.009	-0.025
100	B047	-0.016	-0.010	-0.006
100	B048	-0.016	-0.010	-0.006
100	B049	-0.016	-0.010	-0.006
100	B050	-0.016	-0.010	-0.006
100	B051	-0.016	0.009	-0.025
100	B052	-0.016	-0.010	-0.006
100	B053	-0.016	-0.010	-0.006
100	B054	-0.016	0.009	-0.025
100	B055	-0.016	-0.010	-0.006
100	B056	-0.016	-0.010	-0.006
100	B057	-0.035	-0.010	-0.025
100	B058	-0.016	-0.010	-0.006
100	B059	-0.016	-0.010	-0.006
100	B060	-0.016	-0.010	-0.006
100	B061	-0.016	-0.010	-0.006
100	B062	-0.016	0.002	-0.018
100	B063	-0.016	-0.010	-0.006
100	B064	-0.016	-0.010	-0.006
	Max	-0.002	0.009	-0.003
	Average	-0.015	-0.005	-0.010
	Min	-0.035	-0.010	-0.025
	Std Dev	0.007	0.007	0.008



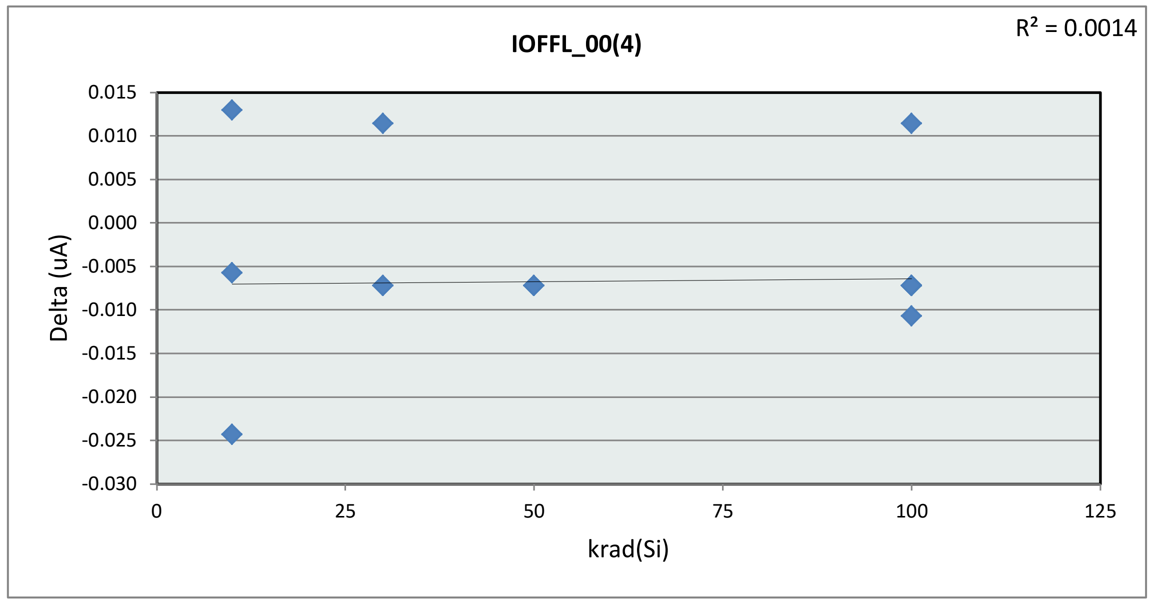
	IOFFL_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.001	-0.010	-0.010	-0.010
Average	0.001	-0.006	-0.006	-0.006
Max	0.001	0.009	0.009	0.009
UL	150.000	150.000	150.000	150.000



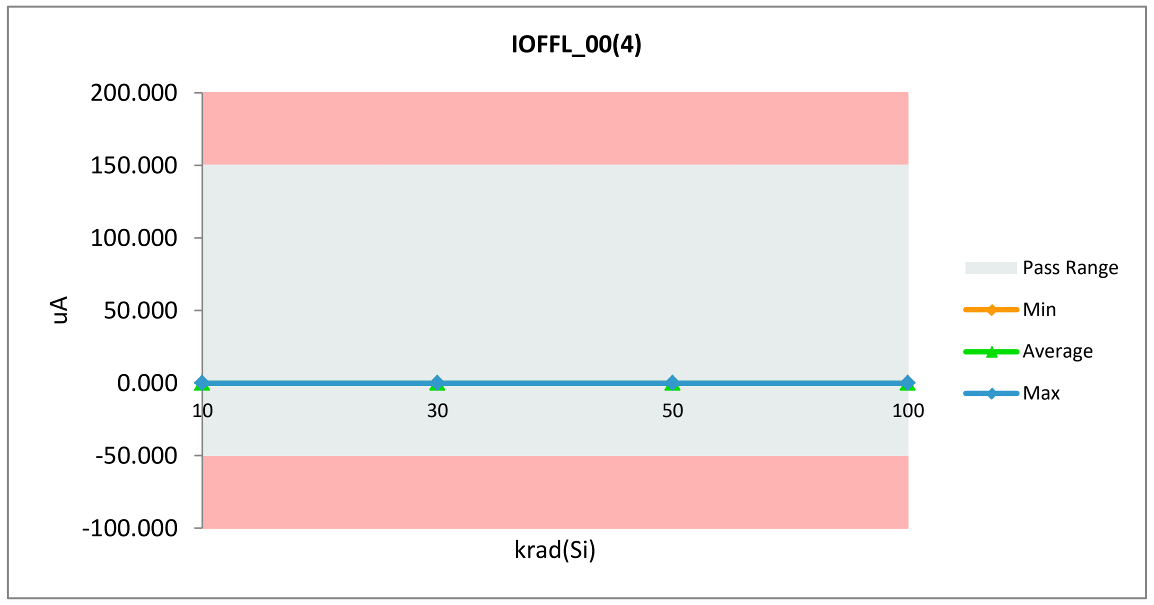
HDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFL_00(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.026	-0.001	-0.024
10	7	-0.026	-0.001	-0.024
10	8	-0.007	-0.001	-0.006
10	9	-0.007	-0.020	0.013
10	10	-0.007	-0.001	-0.006
30	6	-0.019	-0.031	0.011
30	7	-0.019	-0.012	-0.007
30	8	-0.019	-0.012	-0.007
30	9	-0.019	-0.012	-0.007
30	10	-0.019	-0.012	-0.007
50	16	-0.019	-0.012	-0.007
50	17	-0.019	-0.012	-0.007
50	18	-0.019	-0.012	-0.007
50	19	-0.019	-0.012	-0.007
50	20	-0.019	-0.012	-0.007
100	B043	-0.019	-0.012	-0.007
100	B044	-0.019	-0.012	-0.007
100	B045	-0.019	-0.012	-0.007
100	B046	-0.019	-0.012	-0.007
100	B047	-0.019	-0.012	-0.007
100	B048	-0.019	-0.012	-0.007
100	B049	-0.019	-0.012	-0.007
100	B050	-0.019	-0.031	0.011
100	B051	-0.019	-0.012	-0.007
100	B052	-0.019	-0.012	-0.007
100	B053	-0.019	-0.012	-0.007
100	B054	-0.019	-0.012	-0.007
100	B055	-0.019	-0.012	-0.007
100	B056	-0.019	-0.012	-0.007
100	B057	-0.019	-0.012	-0.007
100	B058	-0.019	-0.012	-0.007
100	B059	-0.019	-0.012	-0.007
100	B060	-0.019	-0.012	-0.007
100	B061	-0.019	-0.012	-0.007
100	B062	-0.019	-0.008	-0.011
100	B063	-0.019	-0.012	-0.007
100	B064	-0.019	-0.012	-0.007
	Max	-0.007	-0.001	0.013
	Average	-0.019	-0.012	-0.007
	Min	-0.026	-0.031	-0.024
	Std Dev	0.004	0.006	0.007

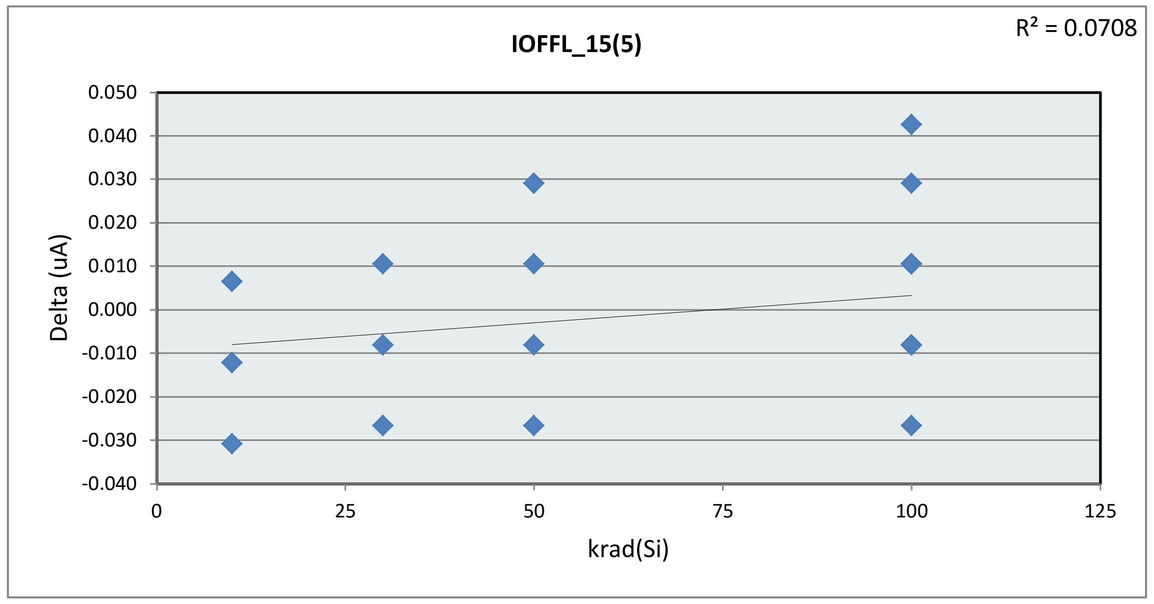


	IOFFL_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.020	-0.031	-0.012	-0.031
Average	-0.005	-0.016	-0.012	-0.013
Max	-0.001	-0.012	-0.012	-0.008
UL	150.000	150.000	150.000	150.000

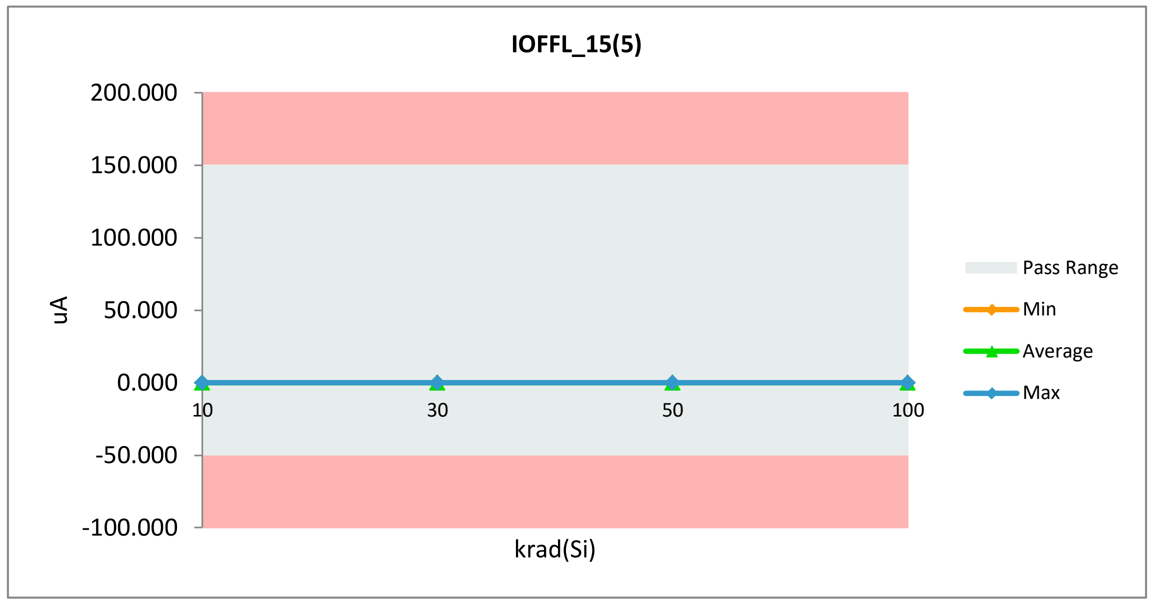


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_15(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.028	0.003	-0.031
10	7	-0.028	-0.016	-0.012
10	8	-0.010	-0.016	0.006
10	9	-0.010	-0.016	0.006
10	10	-0.028	-0.016	-0.012
30	6	-0.015	0.011	-0.027
30	7	0.003	0.011	-0.008
30	8	0.003	0.011	-0.008
30	9	-0.015	0.011	-0.027
30	10	0.003	-0.007	0.011
50	16	0.003	-0.007	0.011
50	17	-0.015	0.011	-0.027
50	18	0.003	-0.026	0.029
50	19	0.022	-0.007	0.029
50	20	0.003	0.011	-0.008
100	B043	0.003	0.011	-0.008
100	B044	0.003	-0.007	0.011
100	B045	0.003	0.011	-0.008
100	B046	-0.015	-0.007	-0.008
100	B047	0.003	0.011	-0.008
100	B048	0.003	-0.007	0.011
100	B049	0.003	-0.007	0.011
100	B050	-0.015	-0.007	-0.008
100	B051	0.003	0.011	-0.008
100	B052	0.003	-0.007	0.011
100	B053	0.003	-0.007	0.011
100	B054	-0.015	0.011	-0.027
100	B055	0.003	-0.007	0.011
100	B056	0.022	-0.007	0.029
100	B057	0.003	-0.007	0.011
100	B058	0.003	0.011	-0.008
100	B059	0.003	0.011	-0.008
100	B060	0.003	-0.007	0.011
100	B061	0.003	0.011	-0.008
100	B062	0.022	-0.021	0.043
100	B063	0.003	-0.007	0.011
100	B064	0.003	0.011	-0.008
	Max	0.022	0.011	0.043
	Average	-0.001	-0.001	0.000
	Min	-0.028	-0.026	-0.031
	Std Dev	0.012	0.012	0.017

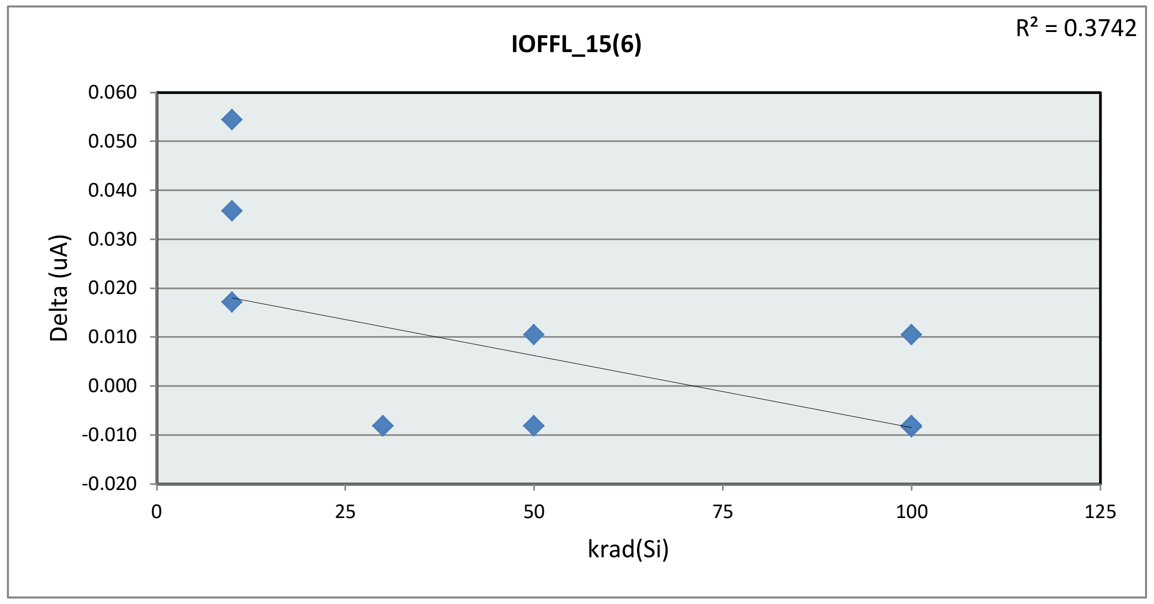


	IOFFL_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.016	-0.007	-0.026	-0.021
Average	-0.012	0.008	-0.003	0.000
Max	0.003	0.011	0.011	0.011
UL	150.000	150.000	150.000	150.000

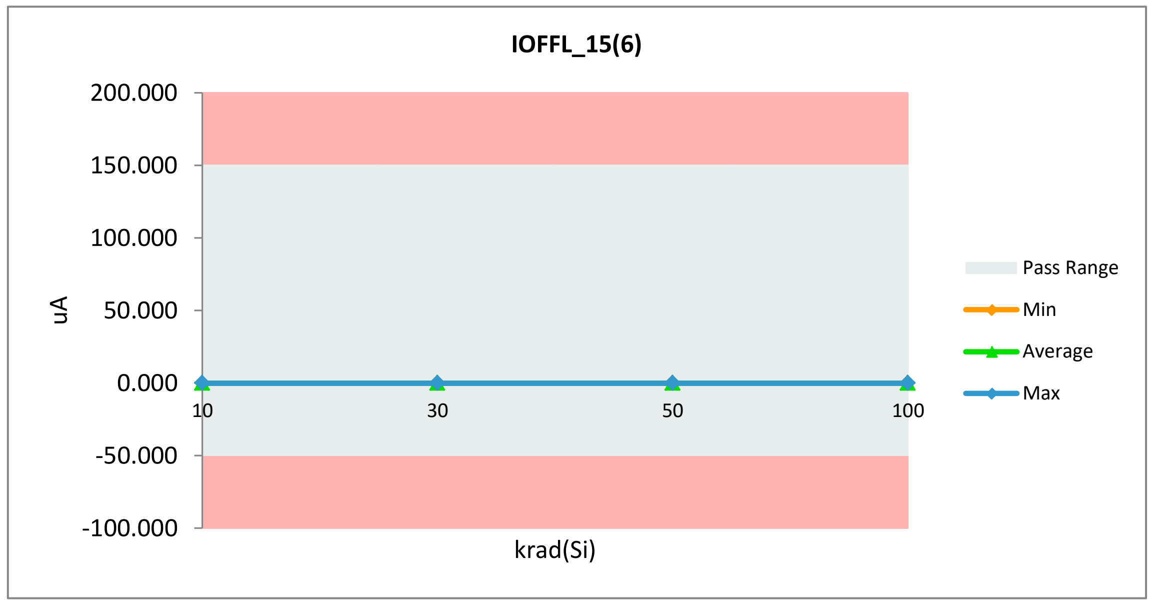


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_15(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.010	-0.027	0.017
10	7	0.008	-0.046	0.054
10	8	0.008	-0.046	0.054
10	9	-0.010	-0.046	0.036
10	10	-0.010	-0.046	0.036
30	6	-0.005	0.003	-0.008
30	7	-0.005	0.003	-0.008
30	8	-0.005	0.003	-0.008
30	9	-0.005	0.003	-0.008
30	10	-0.005	0.003	-0.008
50	16	-0.005	0.003	-0.008
50	17	0.013	0.003	0.011
50	18	-0.005	0.003	-0.008
50	19	-0.005	0.003	-0.008
50	20	-0.005	0.003	-0.008
100	B043	0.013	0.003	0.011
100	B044	-0.005	0.003	-0.008
100	B045	-0.005	0.003	-0.008
100	B046	-0.005	0.003	-0.008
100	B047	-0.005	0.003	-0.008
100	B048	-0.005	0.003	-0.008
100	B049	-0.005	0.003	-0.008
100	B050	-0.005	0.003	-0.008
100	B051	-0.005	0.003	-0.008
100	B052	-0.005	0.003	-0.008
100	B053	-0.005	0.003	-0.008
100	B054	-0.005	0.003	-0.008
100	B055	-0.005	0.003	-0.008
100	B056	-0.005	0.003	-0.008
100	B057	-0.005	0.003	-0.008
100	B058	-0.005	0.003	-0.008
100	B059	-0.005	0.003	-0.008
100	B060	-0.005	0.003	-0.008
100	B061	0.013	0.003	0.011
100	B062	-0.005	0.003	-0.008
100	B063	-0.005	0.003	-0.008
100	B064	-0.005	0.003	-0.008
	Max	0.013	0.003	0.054
	Average	-0.004	-0.003	0.000
	Min	-0.010	-0.046	-0.008
	Std Dev	0.006	0.016	0.017

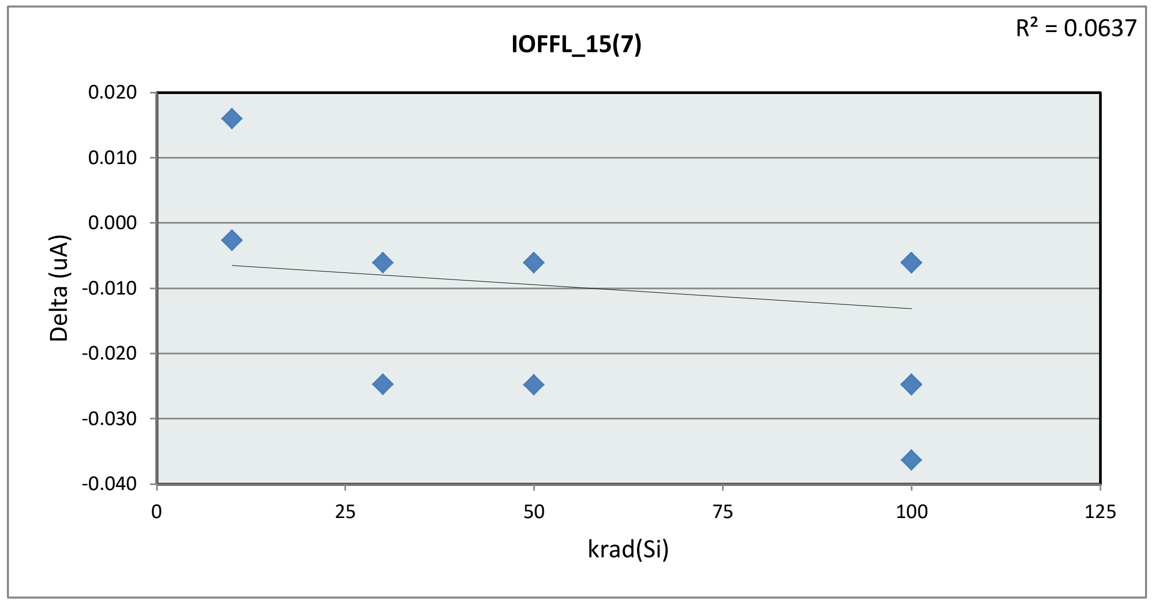


	IOFFL_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.046	0.003	0.003	0.003
Average	-0.042	0.003	0.003	0.003
Max	-0.027	0.003	0.003	0.003
UL	150.000	150.000	150.000	150.000

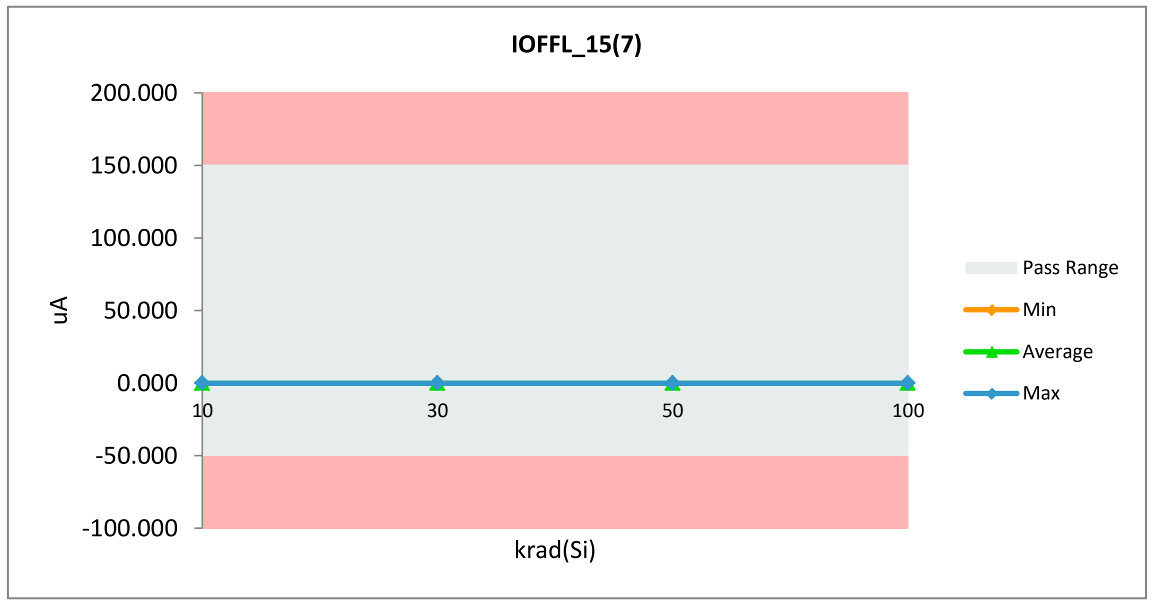


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_15(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-0.002	0.001	-0.003
10	7	0.017	0.001	0.016
10	8	-0.002	0.001	-0.003
10	9	-0.002	0.001	-0.003
10	10	-0.002	0.001	-0.003
30	6	-0.016	0.009	-0.025
30	7	-0.016	0.009	-0.025
30	8	-0.016	-0.010	-0.006
30	9	-0.016	-0.010	-0.006
30	10	-0.016	0.009	-0.025
50	16	-0.016	-0.010	-0.006
50	17	-0.016	-0.010	-0.006
50	18	-0.035	-0.010	-0.025
50	19	-0.016	-0.010	-0.006
50	20	-0.016	-0.010	-0.006
100	B043	-0.016	-0.010	-0.006
100	B044	-0.016	-0.010	-0.006
100	B045	-0.016	-0.010	-0.006
100	B046	-0.016	-0.010	-0.006
100	B047	-0.016	0.009	-0.025
100	B048	-0.016	0.009	-0.025
100	B049	-0.016	-0.010	-0.006
100	B050	-0.016	-0.010	-0.006
100	B051	-0.016	-0.010	-0.006
100	B052	-0.016	-0.010	-0.006
100	B053	-0.016	0.009	-0.025
100	B054	-0.016	-0.010	-0.006
100	B055	-0.016	-0.010	-0.006
100	B056	-0.016	-0.010	-0.006
100	B057	-0.016	-0.010	-0.006
100	B058	-0.016	-0.010	-0.006
100	B059	-0.016	-0.010	-0.006
100	B060	-0.035	-0.010	-0.025
100	B061	-0.016	-0.010	-0.006
100	B062	-0.035	0.002	-0.036
100	B063	-0.016	0.009	-0.025
100	B064	-0.035	-0.010	-0.025
	Max	0.017	0.009	0.016
	Average	-0.016	-0.005	-0.011
	Min	-0.035	-0.010	-0.036
	Std Dev	0.010	0.008	0.011

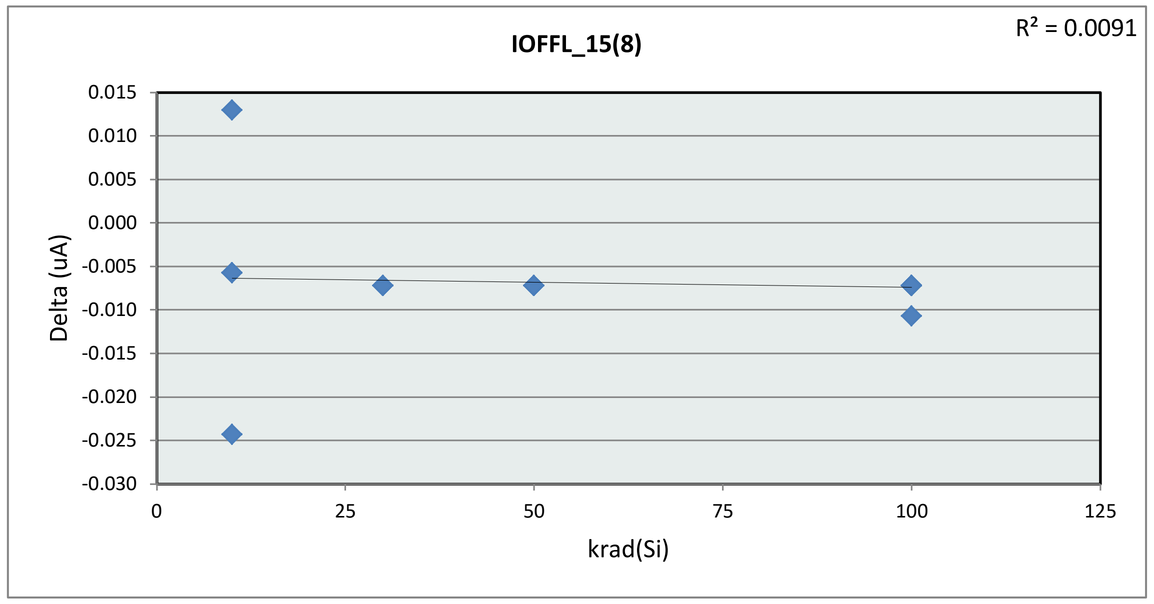


	IOFFL_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.001	-0.010	-0.010	-0.010
Average	0.001	0.001	-0.010	-0.006
Max	0.001	0.009	-0.010	0.009
UL	150.000	150.000	150.000	150.000

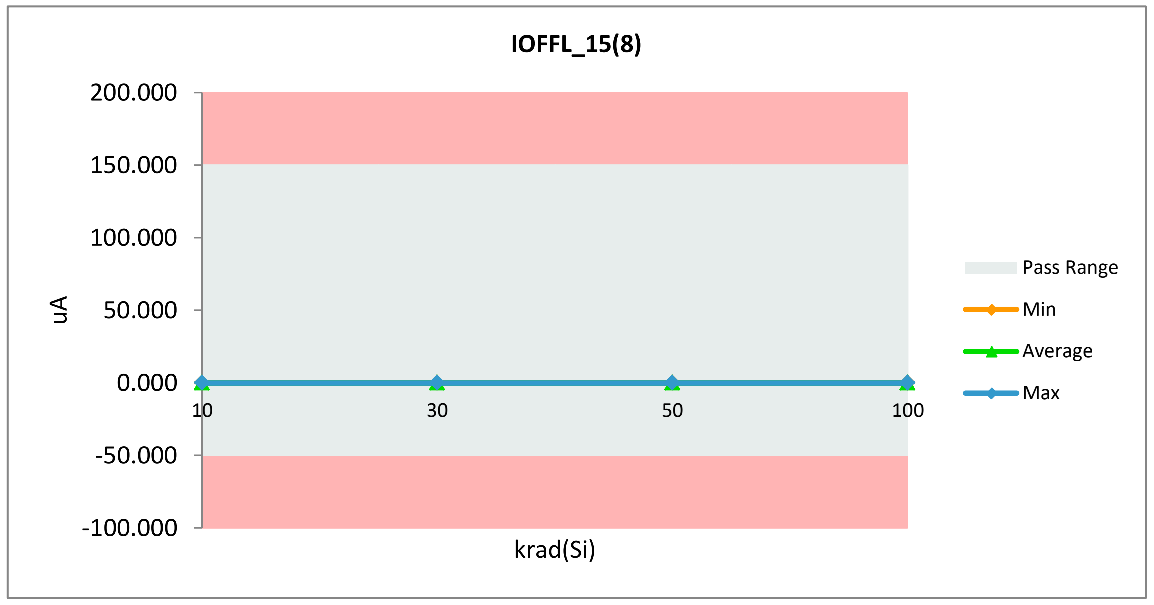


HDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_15(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-0.007	-0.001	-0.006
10	7	-0.007	-0.001	-0.006
10	8	-0.026	-0.001	-0.024
10	9	-0.007	-0.020	0.013
10	10	-0.007	-0.001	-0.006
30	6	-0.019	-0.012	-0.007
30	7	-0.019	-0.012	-0.007
30	8	-0.019	-0.012	-0.007
30	9	-0.019	-0.012	-0.007
30	10	-0.019	-0.012	-0.007
50	16	-0.019	-0.012	-0.007
50	17	-0.019	-0.012	-0.007
50	18	-0.019	-0.012	-0.007
50	19	-0.019	-0.012	-0.007
50	20	-0.019	-0.012	-0.007
100	B043	-0.019	-0.012	-0.007
100	B044	-0.019	-0.012	-0.007
100	B045	-0.019	-0.012	-0.007
100	B046	-0.019	-0.012	-0.007
100	B047	-0.019	-0.012	-0.007
100	B048	-0.019	-0.012	-0.007
100	B049	-0.019	-0.012	-0.007
100	B050	-0.019	-0.012	-0.007
100	B051	-0.019	-0.012	-0.007
100	B052	-0.019	-0.012	-0.007
100	B053	-0.019	-0.012	-0.007
100	B054	-0.019	-0.012	-0.007
100	B055	-0.019	-0.012	-0.007
100	B056	-0.019	-0.012	-0.007
100	B057	-0.019	-0.012	-0.007
100	B058	-0.019	-0.012	-0.007
100	B059	-0.019	-0.012	-0.007
100	B060	-0.019	-0.012	-0.007
100	B061	-0.019	-0.012	-0.007
100	B062	-0.019	-0.008	-0.011
100	B063	-0.019	-0.012	-0.007
100	B064	-0.019	-0.012	-0.007
	Max	-0.007	-0.001	0.013
	Average	-0.018	-0.011	-0.007
	Min	-0.026	-0.020	-0.024
	Std Dev	0.004	0.004	0.004

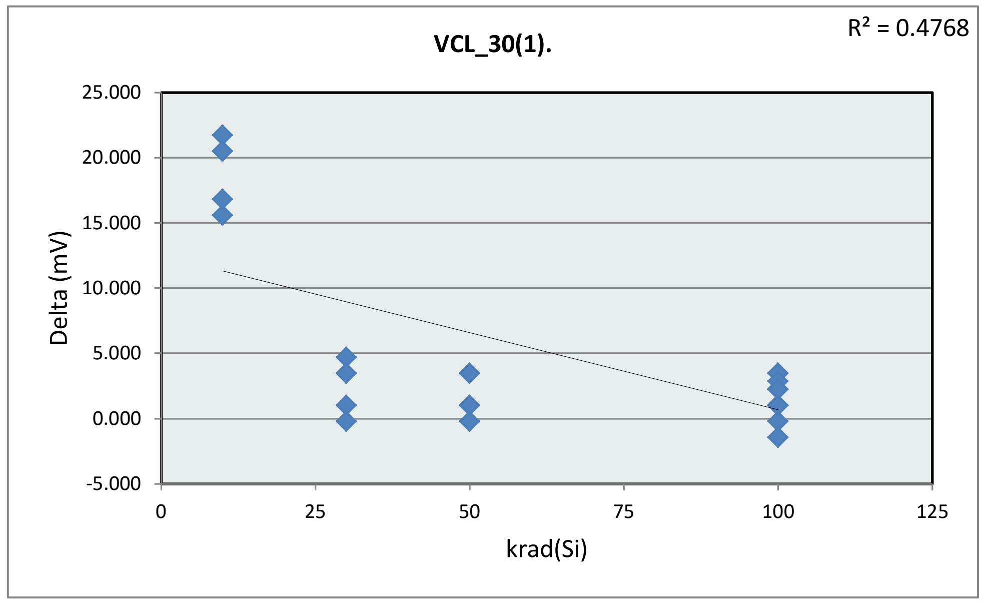


	IOFFL_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.020	-0.012	-0.012	-0.012
Average	-0.005	-0.012	-0.012	-0.012
Max	-0.001	-0.012	-0.012	-0.008
UL	150.000	150.000	150.000	150.000

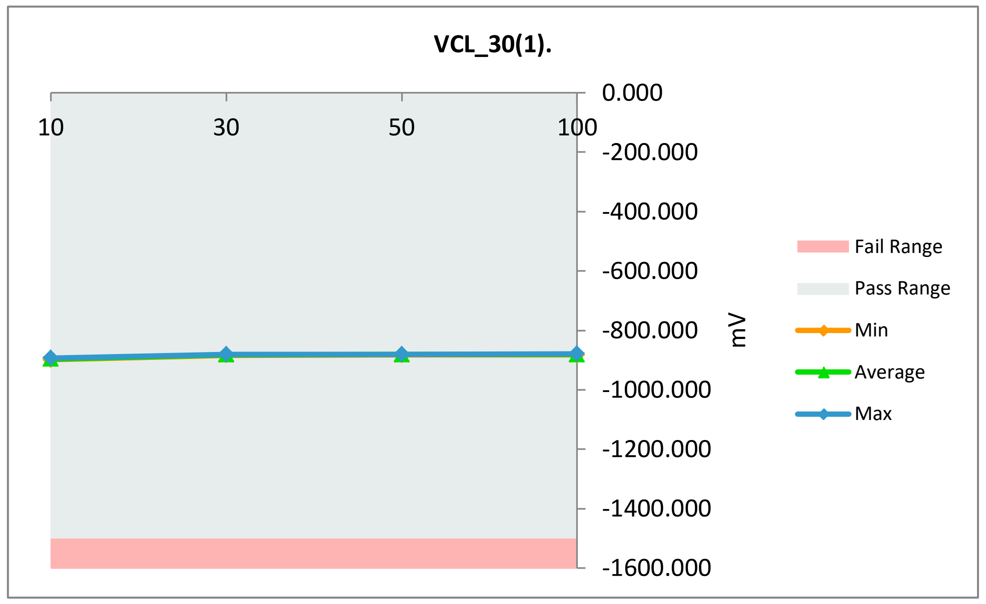


HDR UnBiased TID Report
SN55LVCP22A-SP

		VCL_30(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-877.695	-899.384	21.689
10	7	-877.695	-898.163	20.468
10	8	-878.923	-894.500	15.577
10	9	-875.239	-895.721	20.482
10	10	-876.467	-893.279	16.812
30	6	-879.195	-883.884	4.689
30	7	-879.195	-882.656	3.461
30	8	-879.195	-880.200	1.005
30	9	-880.424	-880.200	-0.224
30	10	-879.195	-882.656	3.461
50	16	-880.424	-880.200	-0.224
50	17	-880.424	-881.428	1.004
50	18	-879.195	-882.656	3.461
50	19	-879.195	-882.656	3.461
50	20	-880.424	-881.428	1.004
100	B043	-880.424	-880.200	-0.224
100	B044	-879.195	-881.428	2.233
100	B045	-877.967	-881.428	3.461
100	B046	-880.424	-881.428	1.004
100	B047	-880.424	-878.971	-1.453
100	B048	-879.195	-881.428	2.233
100	B049	-877.967	-881.428	3.461
100	B050	-880.424	-881.428	1.004
100	B051	-877.967	-881.428	3.461
100	B052	-879.195	-881.428	2.233
100	B053	-881.652	-880.200	-1.452
100	B054	-880.424	-881.428	1.004
100	B055	-879.195	-880.200	1.005
100	B056	-880.424	-881.428	1.004
100	B057	-880.424	-881.428	1.004
100	B058	-880.424	-881.428	1.004
100	B059	-880.424	-881.428	1.004
100	B060	-880.424	-881.428	1.004
100	B061	-879.195	-881.428	2.233
100	B062	-879.195	-882.021	2.826
100	B063	-879.195	-881.428	2.233
100	B064	-880.424	-882.656	2.232
	Max	-875.239	-878.971	21.689
	Average	-879.391	-883.408	4.017
	Min	-881.652	-899.384	-1.453
	Std Dev	1.285	5.276	6.230



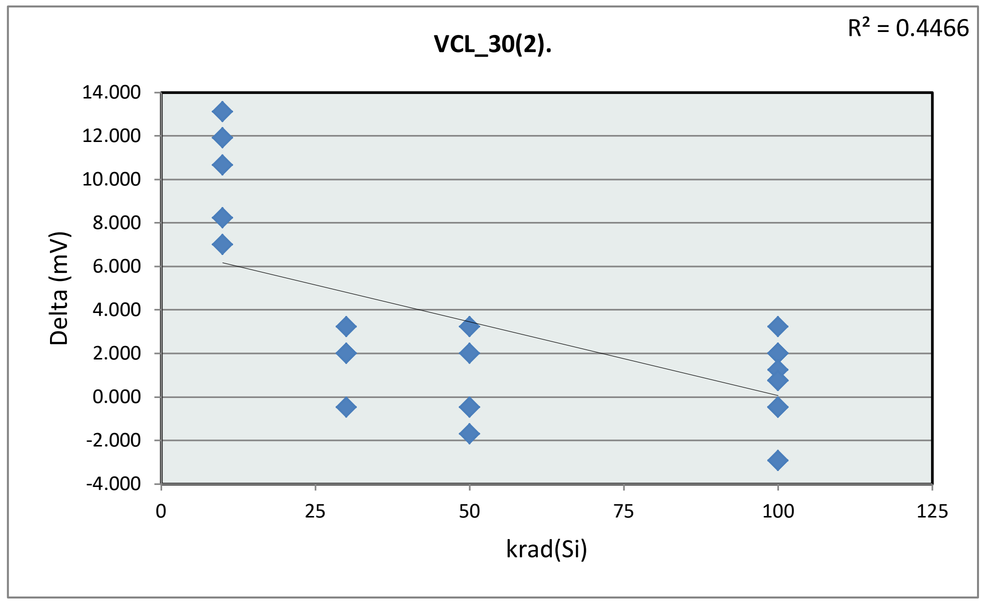
	VCL_30(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-899.384	-883.884	-882.656	-882.656
Average	-896.209	-881.919	-881.674	-881.232
Max	-893.279	-880.200	-880.200	-878.971
UL				



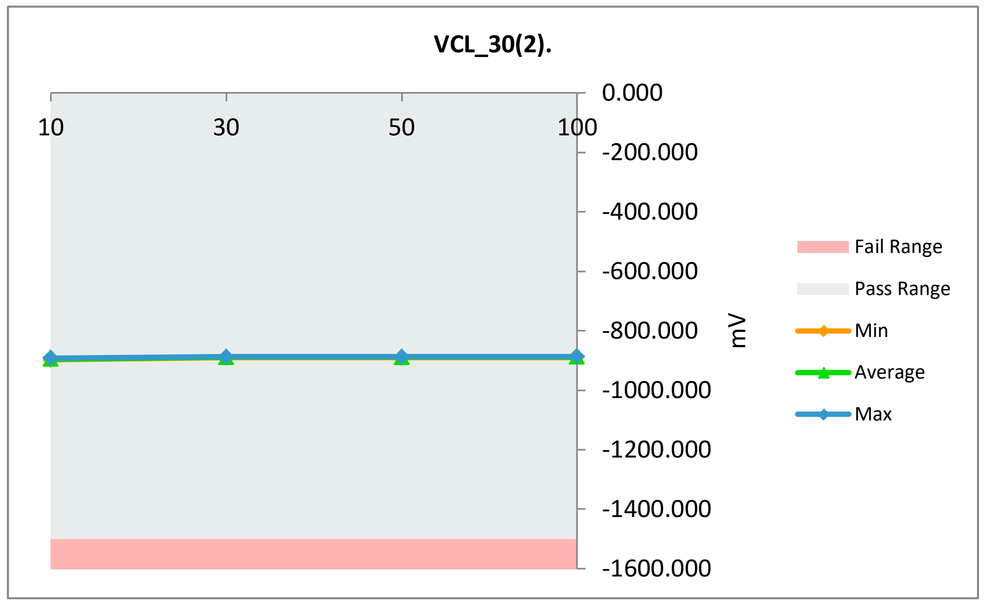
HDR UnBiased TID Report
SN55LVCP22A-SP

	VCL_30(2).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-1500	-1500

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-885.048	-898.155	13.107
10	7	-886.275	-896.934	10.659
10	8	-886.275	-894.491	8.216
10	9	-882.594	-894.491	11.897
10	10	-885.048	-892.049	7.001
30	6	-887.804	-891.020	3.216
30	7	-887.804	-889.793	1.989
30	8	-886.577	-888.566	1.989
30	9	-887.804	-887.340	-0.464
30	10	-887.804	-889.793	1.989
50	16	-889.031	-887.340	-1.691
50	17	-889.031	-888.566	-0.465
50	18	-887.804	-889.793	1.989
50	19	-887.804	-891.020	3.216
50	20	-889.031	-888.566	-0.465
100	B043	-887.804	-887.340	-0.464
100	B044	-886.577	-889.793	3.216
100	B045	-886.577	-888.566	1.989
100	B046	-887.804	-888.566	0.762
100	B047	-889.031	-886.113	-2.918
100	B048	-887.804	-888.566	0.762
100	B049	-886.577	-888.566	1.989
100	B050	-889.031	-888.566	-0.465
100	B051	-886.577	-888.566	1.989
100	B052	-887.804	-888.566	0.762
100	B053	-890.258	-887.340	-2.918
100	B054	-887.804	-889.793	1.989
100	B055	-887.804	-887.340	-0.464
100	B056	-887.804	-888.566	0.762
100	B057	-889.031	-888.566	-0.465
100	B058	-887.804	-888.566	0.762
100	B059	-889.031	-888.566	-0.465
100	B060	-887.804	-888.566	0.762
100	B061	-886.577	-888.566	1.989
100	B062	-887.804	-889.045	1.241
100	B063	-887.804	-888.566	0.762
100	B064	-889.031	-888.566	-0.465
	Max	-882.594	-886.113	13.107
	Average	-887.564	-889.545	1.981
	Min	-890.258	-898.155	-2.918
	Std Dev	1.414	2.594	3.698



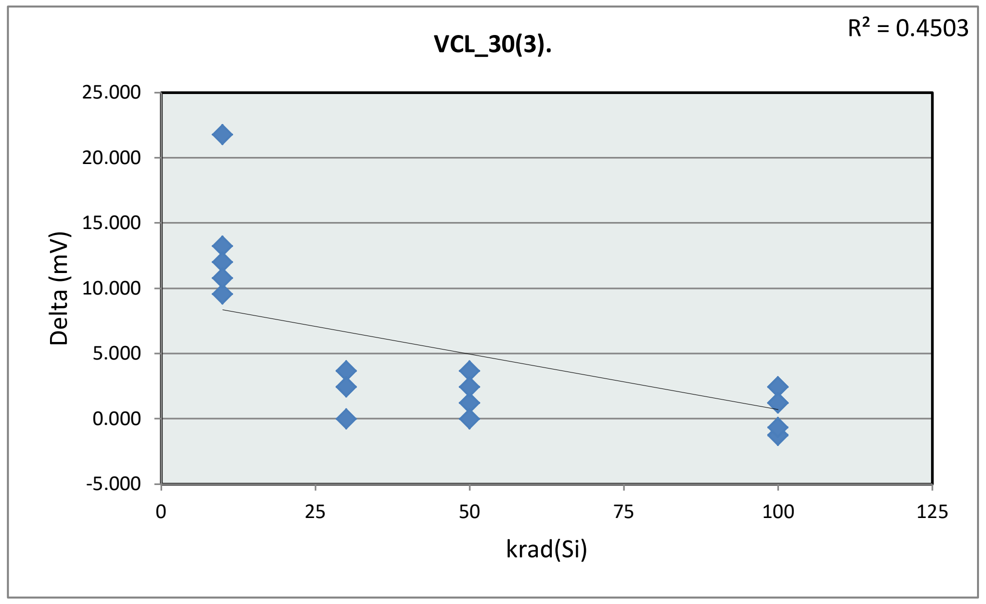
	VCL_30(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-898.155	-891.020	-891.020	-889.793
Average	-895.224	-889.302	-889.057	-888.421
Max	-892.049	-887.340	-887.340	-886.113
UL				



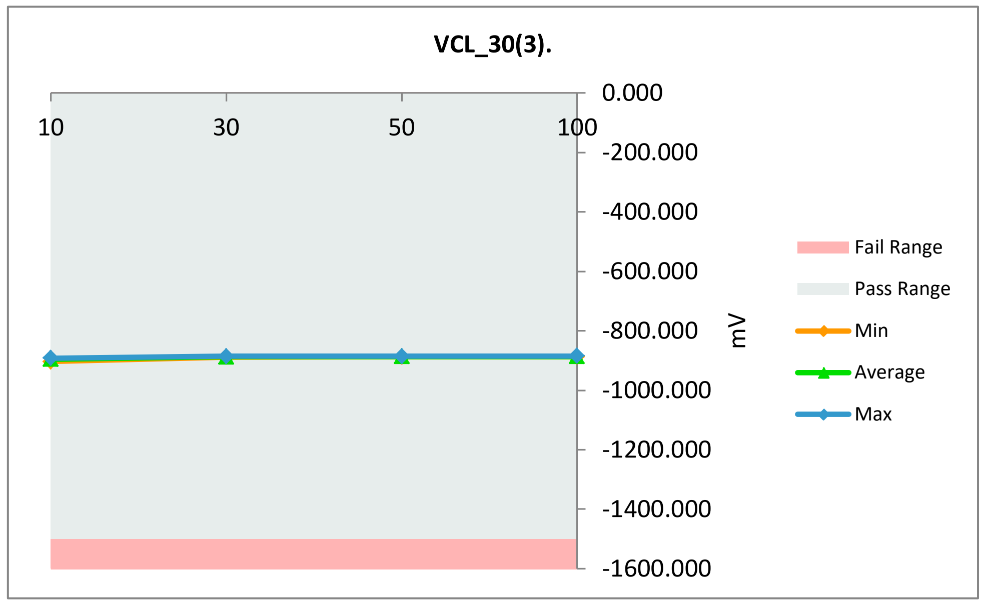
HDR UnBiased TID Report
SN55LVCP22A-SP

	VCL_30(3).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-1500	-1500

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-881.579	-903.336	21.757
10	7	-882.808	-896.012	13.204
10	8	-884.037	-893.571	9.534
10	9	-881.579	-893.571	11.992
10	10	-881.579	-892.350	10.771
30	6	-884.749	-888.397	3.648
30	7	-884.749	-888.397	3.648
30	8	-884.749	-887.167	2.418
30	9	-885.978	-885.937	-0.041
30	10	-884.749	-887.167	2.418
50	16	-885.978	-887.167	1.189
50	17	-884.749	-885.937	1.188
50	18	-883.519	-887.167	3.648
50	19	-884.749	-887.167	2.418
50	20	-885.978	-885.937	-0.041
100	B043	-884.749	-885.937	1.188
100	B044	-884.749	-885.937	1.188
100	B045	-884.749	-887.167	2.418
100	B046	-884.749	-887.167	2.418
100	B047	-885.978	-884.708	-1.270
100	B048	-884.749	-885.937	1.188
100	B049	-884.749	-885.937	1.188
100	B050	-884.749	-885.937	1.188
100	B051	-884.749	-887.167	2.418
100	B052	-884.749	-885.937	1.188
100	B053	-887.208	-885.937	-1.271
100	B054	-884.749	-885.937	1.188
100	B055	-884.749	-885.937	1.188
100	B056	-884.749	-885.937	1.188
100	B057	-884.749	-885.937	1.188
100	B058	-884.749	-887.167	2.418
100	B059	-884.749	-887.167	2.418
100	B060	-884.749	-887.167	2.418
100	B061	-884.749	-887.167	2.418
100	B062	-885.978	-885.288	-0.690
100	B063	-885.978	-887.167	1.189
100	B064	-885.978	-887.167	1.189
	Max	-881.579	-884.708	21.757
	Average	-884.686	-887.813	3.127
	Min	-887.208	-903.336	-1.271
	Std Dev	1.207	3.601	4.590



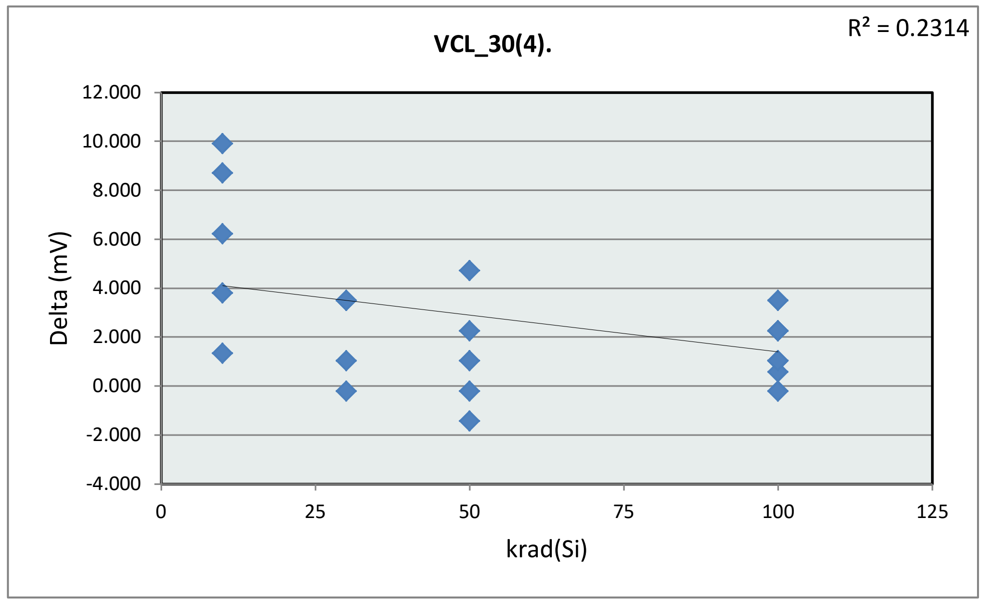
	VCL_30(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-903.336	-888.397	-887.167	-887.167
Average	-895.768	-887.413	-886.675	-886.355
Max	-892.350	-885.937	-885.937	-884.708
UL				



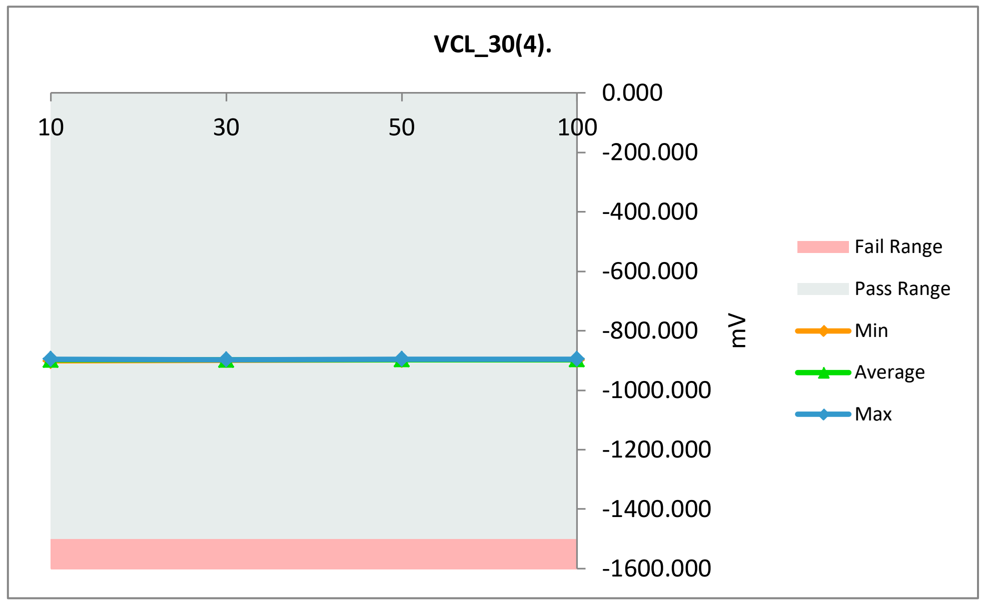
HDR UnBiased TID Report
SN55LVCP22A-SP

	VCL_30(4).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-1500	-1500

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-891.641	-901.539	9.898
10	7	-894.098	-900.319	6.221
10	8	-895.326	-896.660	1.334
10	9	-889.185	-897.880	8.695
10	10	-891.641	-895.440	3.799
30	6	-896.010	-899.491	3.481
30	7	-894.781	-898.263	3.482
30	8	-896.010	-897.034	1.024
30	9	-897.239	-897.034	-0.205
30	10	-894.781	-898.263	3.482
50	16	-897.239	-895.805	-1.434
50	17	-896.010	-897.034	1.024
50	18	-893.553	-898.263	4.710
50	19	-896.010	-898.263	2.253
50	20	-896.010	-895.805	-0.205
100	B043	-896.010	-897.034	1.024
100	B044	-896.010	-897.034	1.024
100	B045	-894.781	-897.034	2.253
100	B046	-896.010	-898.263	2.253
100	B047	-896.010	-895.805	-0.205
100	B048	-896.010	-897.034	1.024
100	B049	-894.781	-897.034	2.253
100	B050	-896.010	-898.263	2.253
100	B051	-894.781	-898.263	3.482
100	B052	-896.010	-897.034	1.024
100	B053	-897.239	-897.034	-0.205
100	B054	-896.010	-897.034	1.024
100	B055	-896.010	-897.034	1.024
100	B056	-896.010	-897.034	1.024
100	B057	-896.010	-898.263	2.253
100	B058	-896.010	-898.263	2.253
100	B059	-896.010	-898.263	2.253
100	B060	-896.010	-898.263	2.253
100	B061	-894.781	-898.263	3.482
100	B062	-896.010	-896.591	0.581
100	B063	-896.010	-898.263	2.253
100	B064	-897.239	-898.263	1.024
	Max	-889.185	-895.440	9.898
	Average	-895.386	-897.634	2.248
	Min	-897.239	-901.539	-1.434
	Std Dev	1.630	1.214	2.286

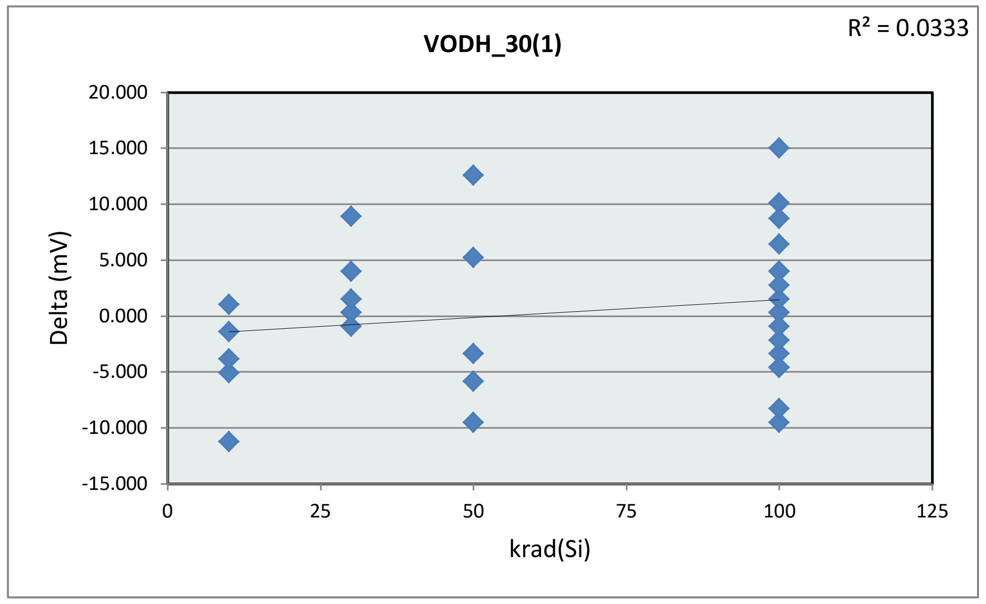


	VCL_30(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-901.539	-899.491	-898.263	-898.263
Average	-898.368	-898.017	-897.034	-897.517
Max	-895.440	-897.034	-895.805	-895.805
UL				

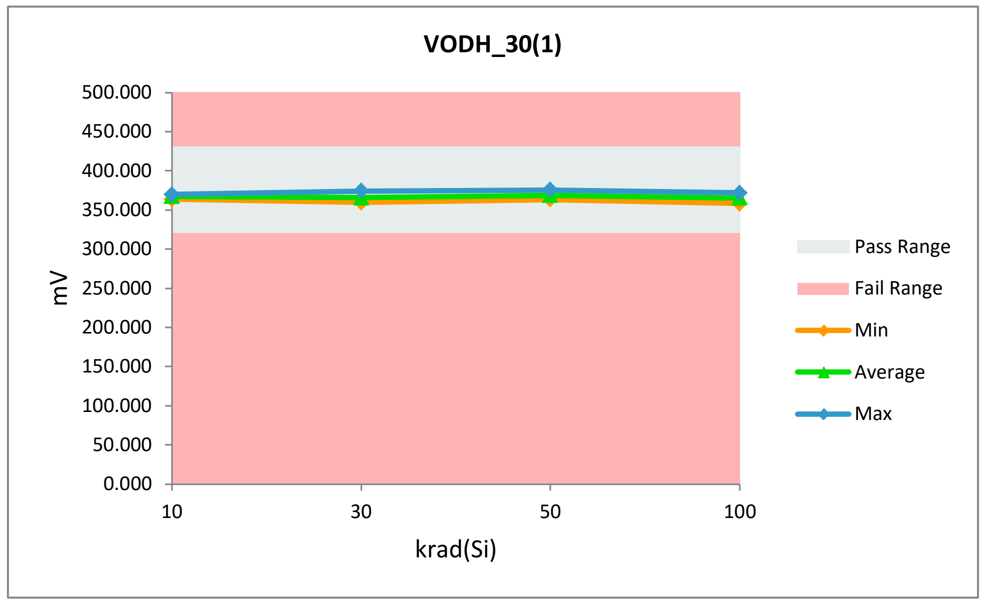


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	361.034	366.138	-5.104
10	7	364.715	363.691	1.024
10	8	357.350	368.579	-11.229
10	9	367.168	368.580	-1.412
10	10	365.943	369.802	-3.859
30	6	367.143	366.848	0.295
30	7	373.284	374.215	-0.931
30	8	363.462	359.486	3.976
30	9	364.689	363.168	1.521
30	10	373.282	364.393	8.889
50	16	363.464	366.848	-3.384
50	17	372.057	366.850	5.207
50	18	375.738	363.169	12.569
50	19	365.920	371.762	-5.842
50	20	365.915	375.443	-9.528
100	B043	368.373	361.937	6.436
100	B044	365.917	365.623	0.294
100	B045	361.006	360.715	0.291
100	B046	364.691	369.305	-4.614
100	B047	362.237	365.622	-3.385
100	B048	369.602	359.484	10.118
100	B049	369.601	371.763	-2.162
100	B050	369.601	365.624	3.977
100	B051	372.054	361.943	10.111
100	B052	364.689	369.307	-4.618
100	B053	359.782	369.306	-9.524
100	B054	370.830	369.306	1.524
100	B055	367.146	371.758	-4.612
100	B056	367.144	363.167	3.977
100	B057	362.232	358.261	3.971
100	B058	362.236	370.534	-8.298
100	B059	362.235	366.851	-4.616
100	B060	364.687	365.621	-0.934
100	B061	376.965	361.936	15.029
100	B062	370.829	362.123	8.706
100	B063	365.918	361.941	3.977
100	B064	367.146	364.392	2.754
	Max	376.965	375.443	15.029
	Average	366.651	366.094	0.557
	Min	357.350	358.261	-11.229
	Std Dev	4.465	4.215	6.370

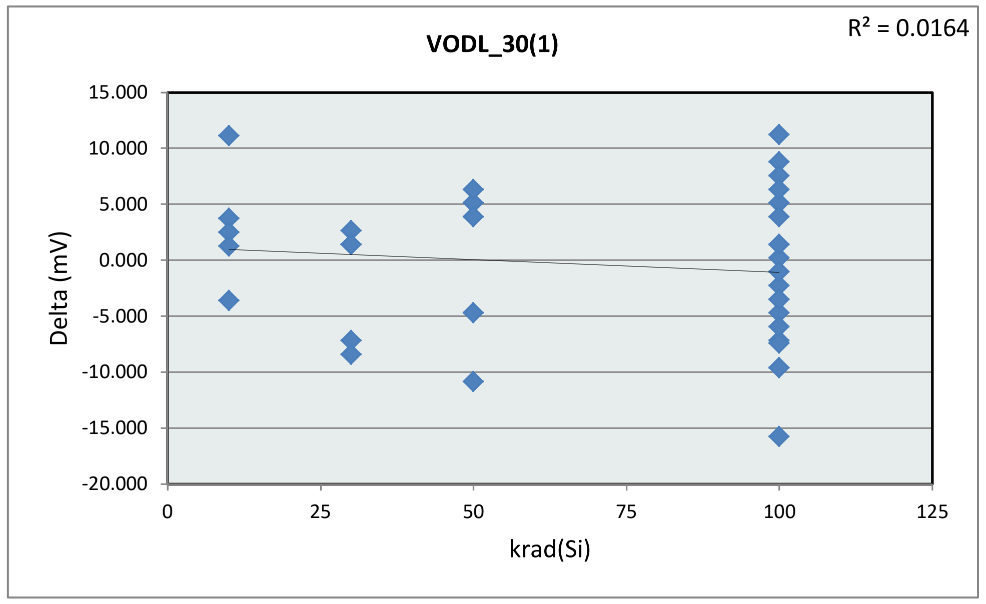


	VODH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	363.691	359.486	363.169	358.261
Average	367.358	365.622	368.814	365.296
Max	369.802	374.215	375.443	371.763
UL	430.000	430.000	430.000	430.000

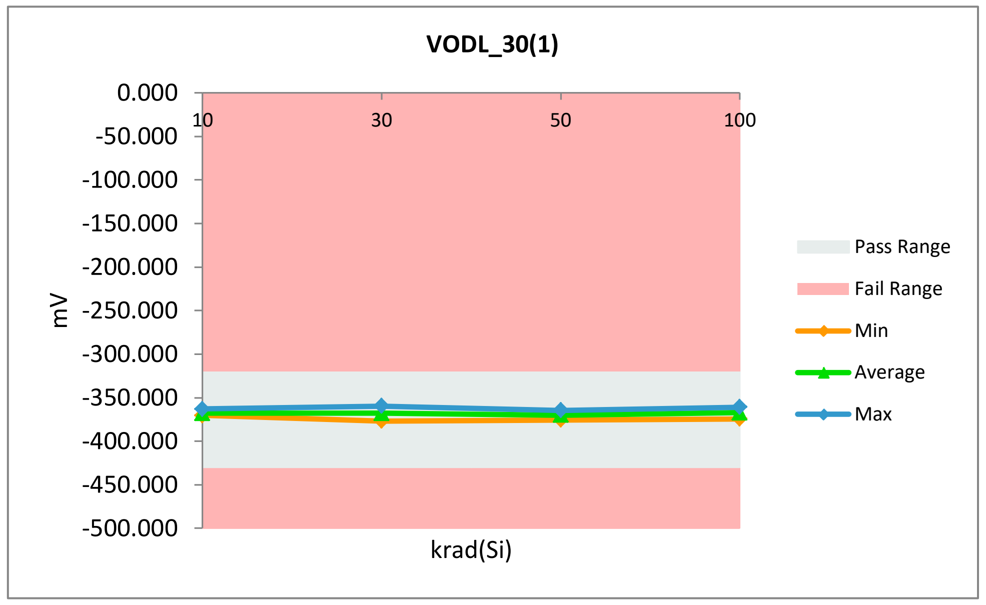


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-363.028	-366.770	3.742
10	7	-366.710	-363.109	-3.601
10	8	-358.121	-369.215	11.094
10	9	-366.711	-369.214	2.503
10	10	-369.164	-370.435	1.271
30	6	-368.022	-369.431	1.409
30	7	-374.154	-376.788	2.634
30	8	-366.793	-359.612	-7.181
30	9	-365.567	-366.975	1.408
30	10	-375.383	-366.976	-8.407
50	16	-364.337	-369.430	5.093
50	17	-372.926	-368.201	-4.725
50	18	-375.382	-364.519	-10.863
50	19	-369.245	-373.106	3.861
50	20	-369.249	-375.561	6.312
100	B043	-370.473	-363.297	-7.176
100	B044	-368.021	-366.974	-1.047
100	B045	-363.113	-363.292	0.179
100	B046	-366.792	-371.881	5.089
100	B047	-363.109	-368.202	5.093
100	B048	-372.926	-363.296	-9.630
100	B049	-371.700	-373.105	1.405
100	B050	-371.700	-366.973	-4.727
100	B051	-371.702	-362.063	-9.639
100	B052	-365.566	-374.334	8.768
100	B053	-360.655	-371.881	11.226
100	B054	-372.926	-370.653	-2.273
100	B055	-368.019	-371.883	3.864
100	B056	-368.021	-364.521	-3.500
100	B057	-364.342	-360.837	-3.505
100	B058	-364.337	-371.879	7.542
100	B059	-361.883	-368.200	6.317
100	B060	-368.022	-366.976	-1.046
100	B061	-379.064	-363.298	-15.766
100	B062	-371.700	-364.259	-7.441
100	B063	-368.019	-362.066	-5.953
100	B064	-366.792	-368.204	1.412
	Max	-358.121	-359.612	11.226
	Average	-368.207	-367.768	-0.439
	Min	-379.064	-376.788	-15.766
	Std Dev	4.494	4.264	6.468



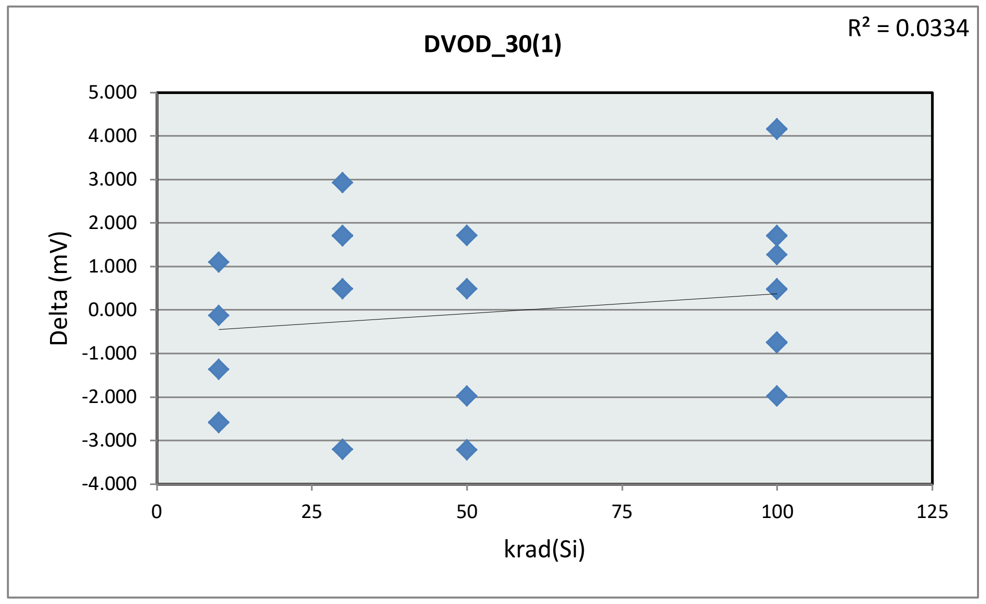
	VODL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-370.435	-376.788	-375.561	-374.334
Average	-367.749	-367.956	-370.163	-367.185
Max	-363.109	-359.612	-364.519	-360.837
UL	-320.000	-320.000	-320.000	-320.000



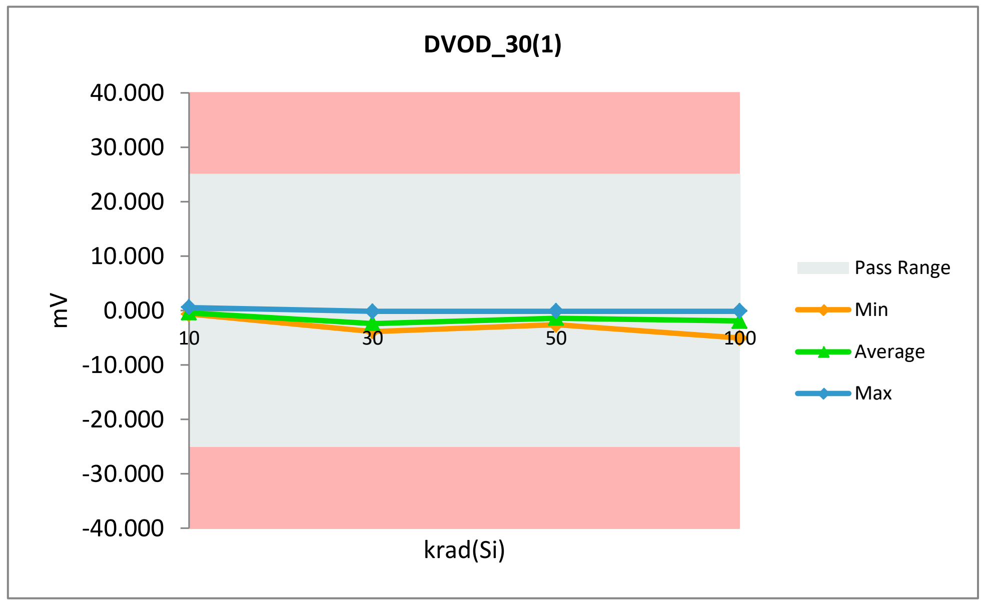
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVOD_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-1.994	-0.632	-1.362
10	7	-1.996	0.582	-2.578
10	8	-0.770	-0.636	-0.134
10	9	0.457	-0.634	1.091
10	10	-3.221	-0.632	-2.589
30	6	-0.878	-2.582	1.704
30	7	-0.871	-2.573	1.702
30	8	-3.331	-0.126	-3.204
30	9	-0.878	-3.807	2.929
30	10	-2.102	-2.583	0.481
50	16	-0.874	-2.582	1.708
50	17	-0.870	-1.351	0.481
50	18	0.357	-1.350	1.707
50	19	-3.325	-1.345	-1.980
50	20	-3.334	-0.119	-3.215
100	B043	-2.100	-1.359	-0.741
100	B044	-2.104	-1.350	-0.754
100	B045	-2.108	-2.577	0.469
100	B046	-2.100	-2.576	0.476
100	B047	-0.871	-2.580	1.709
100	B048	-3.324	-3.812	0.488
100	B049	-2.099	-1.341	-0.758
100	B050	-2.099	-1.349	-0.750
100	B051	0.353	-0.120	0.472
100	B052	-0.877	-5.027	4.150
100	B053	-0.874	-2.575	1.701
100	B054	-2.097	-1.347	-0.750
100	B055	-0.873	-0.124	-0.748
100	B056	-0.878	-1.354	0.476
100	B057	-2.110	-2.577	0.467
100	B058	-2.100	-1.345	-0.755
100	B059	0.352	-1.348	1.700
100	B060	-3.335	-1.355	-1.980
100	B061	-2.099	-1.362	-0.737
100	B062	-0.872	-2.136	1.264
100	B063	-2.101	-0.125	-1.976
100	B064	0.354	-3.812	4.166
	Max	0.457	0.582	4.166
	Average	-1.557	-1.674	0.117
	Min	-3.335	-5.027	-3.215
	Std Dev	1.141	1.240	1.823

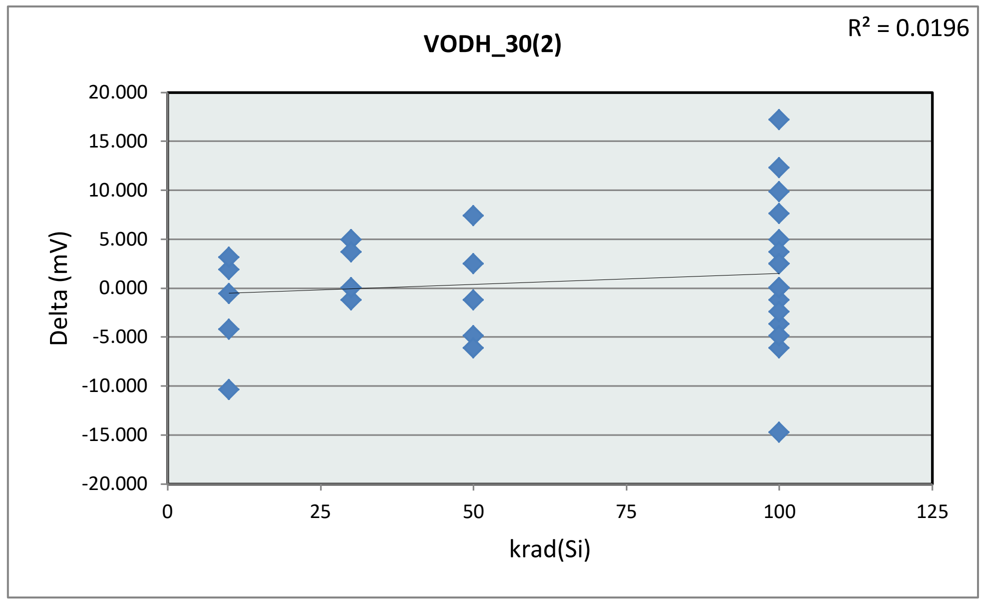


	DVOD_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.636	-3.807	-2.582	-5.027
Average	-0.390	-2.334	-1.349	-1.889
Max	0.582	-0.126	-0.119	-0.120
UL	25.000	25.000	25.000	25.000

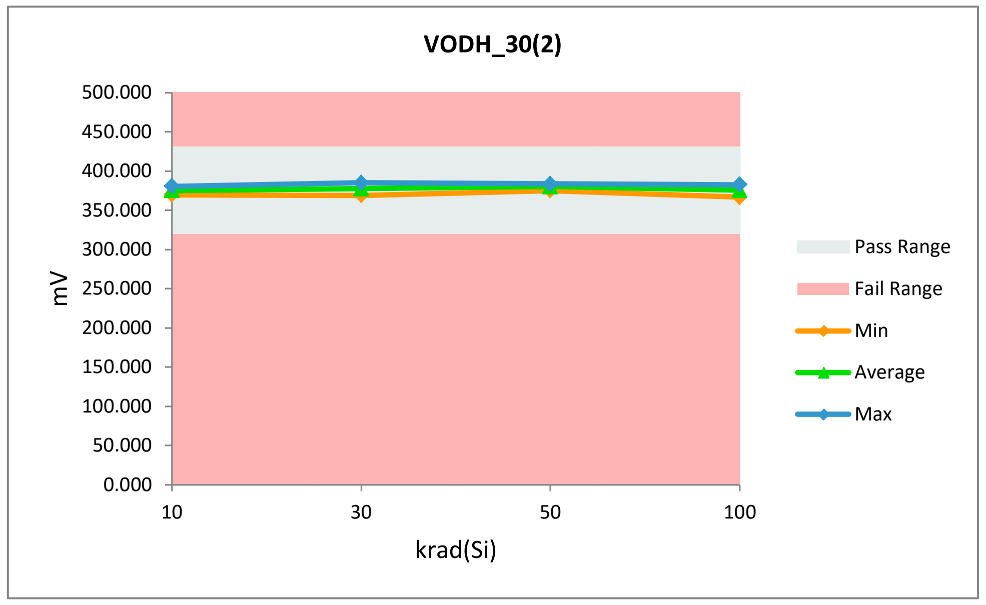


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	371.419	369.544	1.875
10	7	375.099	371.975	3.124
10	8	366.506	376.871	-10.365
10	9	375.097	375.641	-0.544
10	10	376.330	380.546	-4.216
30	6	378.832	380.038	-1.206
30	7	384.975	384.948	0.027
30	8	373.924	368.992	4.932
30	9	378.837	373.902	4.935
30	10	382.512	378.811	3.701
50	16	378.834	380.038	-1.204
50	17	382.517	375.129	7.388
50	18	382.518	380.038	2.480
50	19	378.838	383.721	-4.883
50	20	376.377	382.493	-6.116
100	B043	378.835	368.992	9.843
100	B044	377.604	375.129	2.475
100	B045	367.780	368.992	-1.212
100	B046	378.829	378.811	0.018
100	B047	377.600	377.584	0.016
100	B048	380.061	367.765	12.296
100	B049	383.749	381.266	2.483
100	B050	378.831	378.811	0.020
100	B051	377.611	377.583	0.028
100	B052	376.381	380.038	-3.657
100	B053	367.786	382.493	-14.707
100	B054	382.521	377.584	4.937
100	B055	380.061	377.584	2.477
100	B056	375.152	375.129	0.023
100	B057	370.237	366.538	3.699
100	B058	375.155	381.266	-6.111
100	B059	375.147	380.038	-4.891
100	B060	375.152	375.129	0.023
100	B061	386.202	368.992	17.210
100	B062	380.065	372.469	7.596
100	B063	376.380	373.901	2.479
100	B064	372.694	375.129	-2.435
	Max	386.202	384.948	17.210
	Average	377.201	376.322	0.879
	Min	366.506	366.538	-14.707
	Std Dev	4.638	4.857	5.917



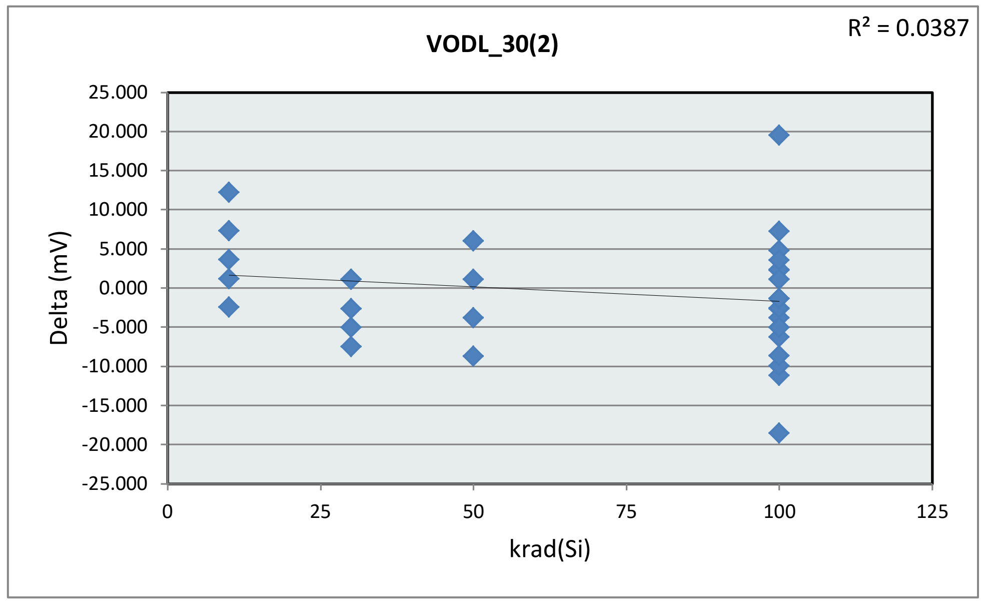
	VODH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	369.544	368.992	375.129	366.538
Average	374.915	377.338	380.284	375.510
Max	380.546	384.948	383.721	382.493
UL	430.000	430.000	430.000	430.000



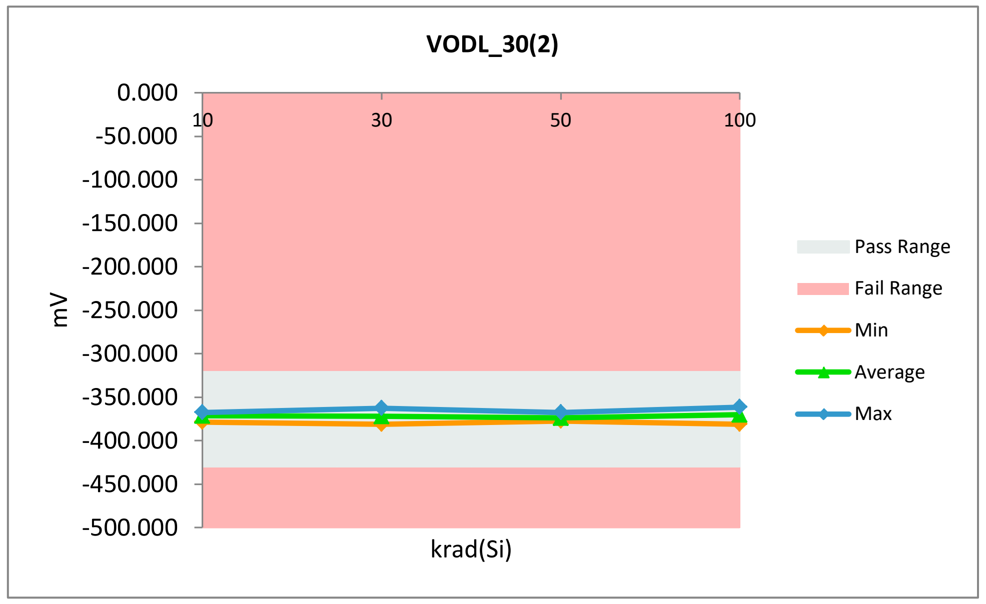
HDR UnBiased TID Report
SN55LVCP22A-SP

	VODL_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-363.771	-367.406	3.635
10	7	-369.909	-367.440	-2.469
10	8	-360.091	-372.321	12.230
10	9	-369.912	-371.107	1.195
10	10	-371.133	-378.423	7.290
30	6	-373.715	-374.784	1.069
30	7	-379.848	-380.921	1.073
30	8	-367.575	-362.510	-5.065
30	9	-374.938	-367.420	-7.518
30	10	-377.401	-374.784	-2.617
50	16	-373.713	-374.784	1.071
50	17	-376.169	-367.420	-8.749
50	18	-377.395	-373.557	-3.838
50	19	-371.254	-377.239	5.985
50	20	-370.032	-376.011	5.979
100	B043	-373.711	-362.511	-11.200
100	B044	-373.715	-368.647	-5.068
100	B045	-363.897	-366.193	2.296
100	B046	-374.946	-372.329	-2.617
100	B047	-371.264	-373.557	2.293
100	B048	-373.714	-363.738	-9.976
100	B049	-381.075	-374.784	-6.291
100	B050	-373.717	-374.784	1.067
100	B051	-374.936	-371.102	-3.834
100	B052	-371.256	-373.557	2.301
100	B053	-361.436	-380.921	19.485
100	B054	-376.164	-373.557	-2.607
100	B055	-376.169	-374.784	-1.385
100	B056	-371.257	-369.874	-1.383
100	B057	-362.668	-361.283	-1.385
100	B058	-367.571	-374.784	7.213
100	B059	-368.807	-373.557	4.750
100	B060	-368.802	-369.875	1.073
100	B061	-379.850	-361.283	-18.567
100	B062	-374.937	-366.282	-8.655
100	B063	-372.484	-367.420	-5.064
100	B064	-366.349	-369.875	3.526
	Max	-360.091	-361.283	19.485
	Average	-371.772	-371.103	-0.669
	Min	-381.075	-380.921	-18.567
	Std Dev	5.130	5.155	6.905

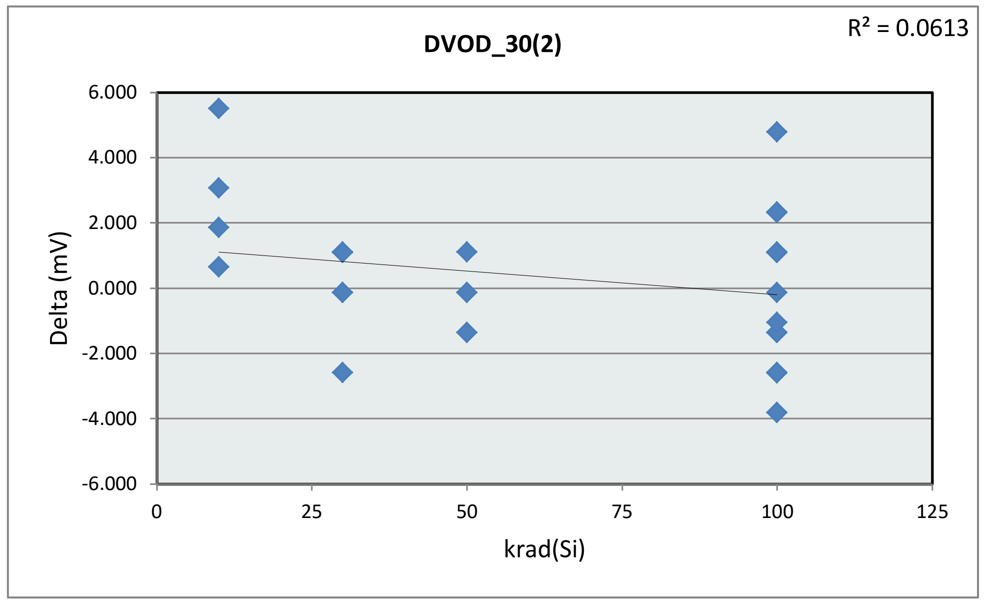


	VODL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-378.423	-380.921	-377.239	-380.921
Average	-371.339	-372.084	-373.802	-370.214
Max	-367.406	-362.510	-367.420	-361.283
UL	-320.000	-320.000	-320.000	-320.000

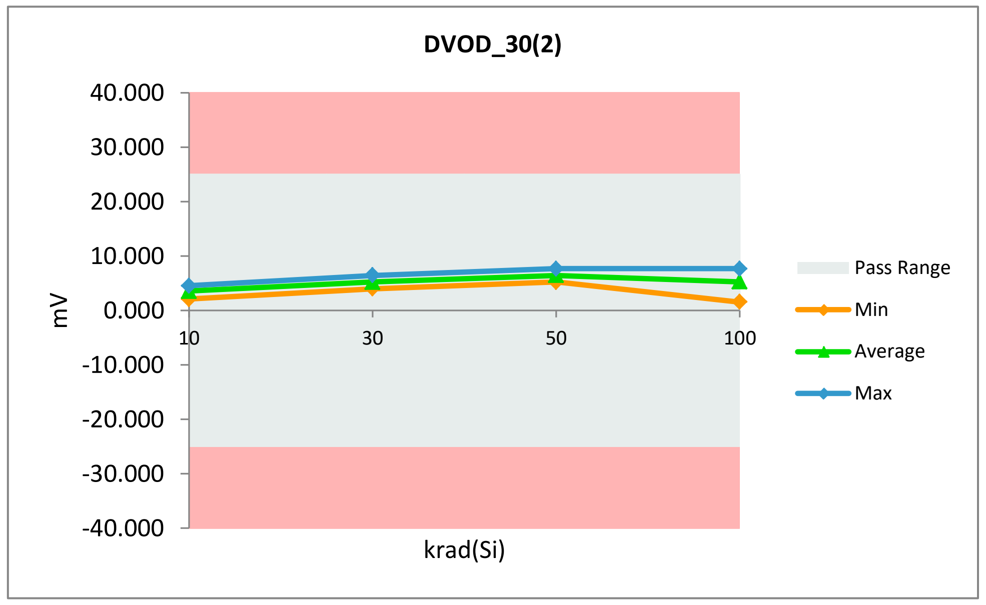


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	7.648	2.138	5.510
10	7	5.190	4.535	0.655
10	8	6.415	4.550	1.865
10	9	5.185	4.533	0.652
10	10	5.197	2.123	3.074
30	6	5.117	5.254	-0.137
30	7	5.127	4.027	1.100
30	8	6.349	6.482	-0.133
30	9	3.899	6.482	-2.583
30	10	5.112	4.027	1.085
50	16	5.122	5.255	-0.133
50	17	6.348	7.709	-1.361
50	18	5.122	6.482	-1.360
50	19	7.584	6.482	1.102
50	20	6.346	6.482	-0.136
100	B043	5.124	6.481	-1.357
100	B044	3.890	6.482	-2.592
100	B045	3.883	2.799	1.084
100	B046	3.883	6.482	-2.599
100	B047	6.336	4.027	2.309
100	B048	6.346	4.027	2.319
100	B049	2.674	6.482	-3.808
100	B050	5.114	4.027	1.087
100	B051	2.675	6.481	-3.806
100	B052	5.125	6.482	-1.357
100	B053	6.350	1.573	4.777
100	B054	6.357	4.027	2.330
100	B055	3.893	2.800	1.093
100	B056	3.895	5.255	-1.360
100	B057	7.569	5.255	2.314
100	B058	7.584	6.482	1.102
100	B059	6.340	6.482	-0.142
100	B060	6.349	5.255	1.094
100	B061	6.352	7.709	-1.357
100	B062	5.128	6.187	-1.059
100	B063	3.896	6.481	-2.585
100	B064	6.345	5.254	1.091
	Max	7.648	7.709	5.510
	Average	5.429	5.219	0.210
	Min	2.674	1.573	-3.808
	Std Dev	1.310	1.578	2.145



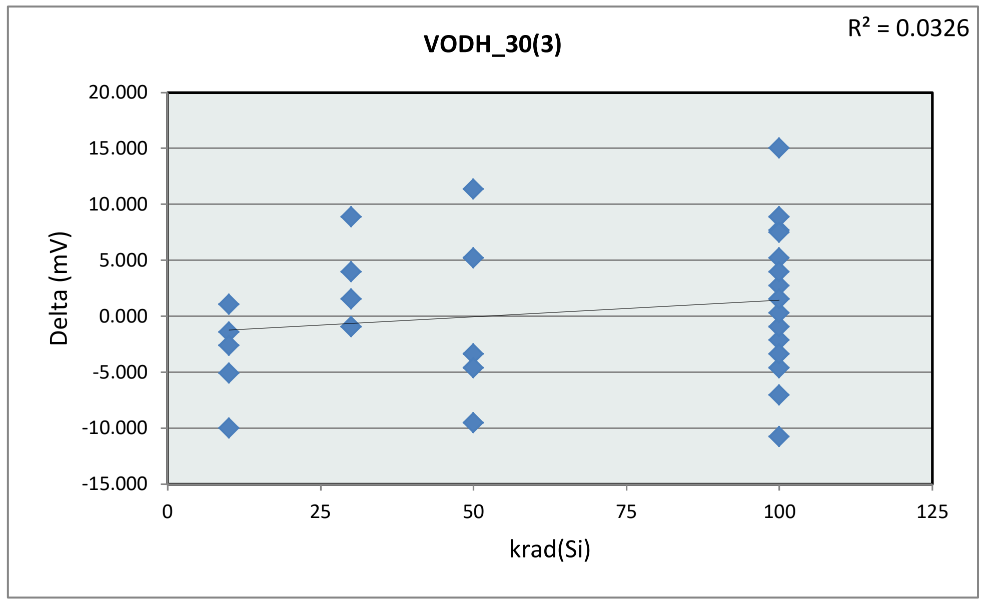
	DVOD_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.123	4.027	5.255	1.573
Average	3.576	5.254	6.482	5.297
Max	4.550	6.482	7.709	7.709
UL	25.000	25.000	25.000	25.000



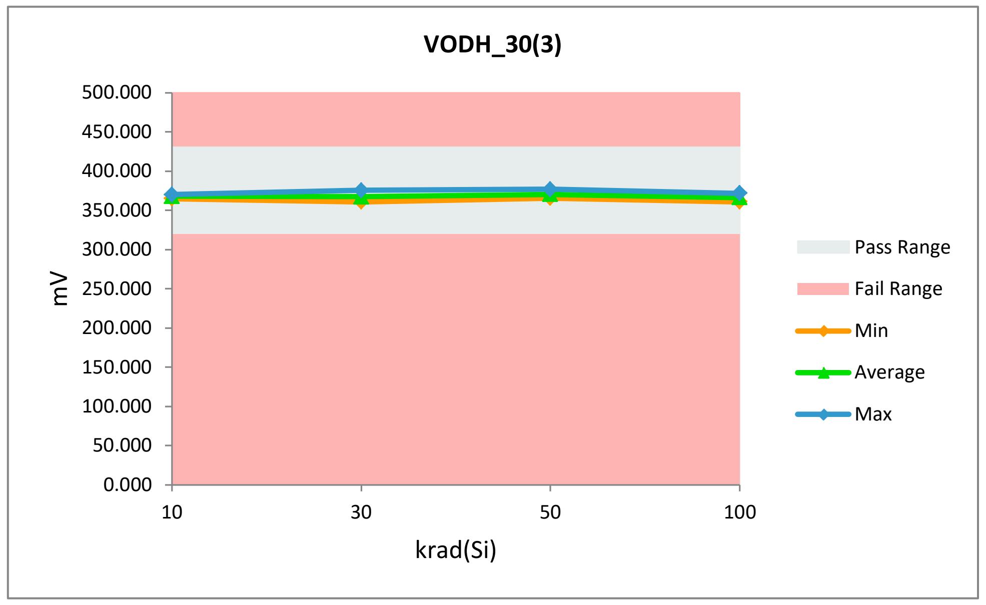
HDR UnBiased TID Report
SN55LVCP22A-SP

	VODH_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	362.260	367.355	-5.095
10	7	365.941	364.909	1.032
10	8	358.577	368.575	-9.998
10	9	368.395	369.797	-1.402
10	10	367.169	369.798	-2.629
30	6	368.369	369.300	-0.931
30	7	374.509	375.440	-0.931
30	8	364.688	360.711	3.977
30	9	365.914	364.392	1.522
30	10	374.507	365.618	8.889
50	16	364.689	368.073	-3.384
50	17	373.282	368.075	5.207
50	18	376.963	365.621	11.342
50	19	368.372	372.986	-4.614
50	20	367.141	376.667	-9.526
100	B043	369.599	361.935	7.664
100	B044	367.142	365.621	1.521
100	B045	361.004	361.939	-0.935
100	B046	365.917	370.530	-4.613
100	B047	363.463	365.619	-2.156
100	B048	370.827	361.936	8.891
100	B049	370.826	371.761	-0.935
100	B050	372.054	366.848	5.206
100	B051	372.052	363.168	8.884
100	B052	365.915	369.304	-3.389
100	B053	359.780	370.530	-10.750
100	B054	372.055	370.531	1.524
100	B055	367.144	371.756	-4.612
100	B056	367.142	365.618	1.524
100	B057	363.457	360.713	2.744
100	B058	364.690	371.759	-7.069
100	B059	363.461	366.849	-3.388
100	B060	367.140	366.845	0.295
100	B061	378.191	363.161	15.030
100	B062	370.826	363.348	7.478
100	B063	367.144	363.166	3.978
100	B064	368.371	366.844	1.527
	Max	378.191	376.667	15.030
	Average	367.810	367.219	0.591
	Min	358.577	360.711	-10.750
	Std Dev	4.494	3.977	6.002



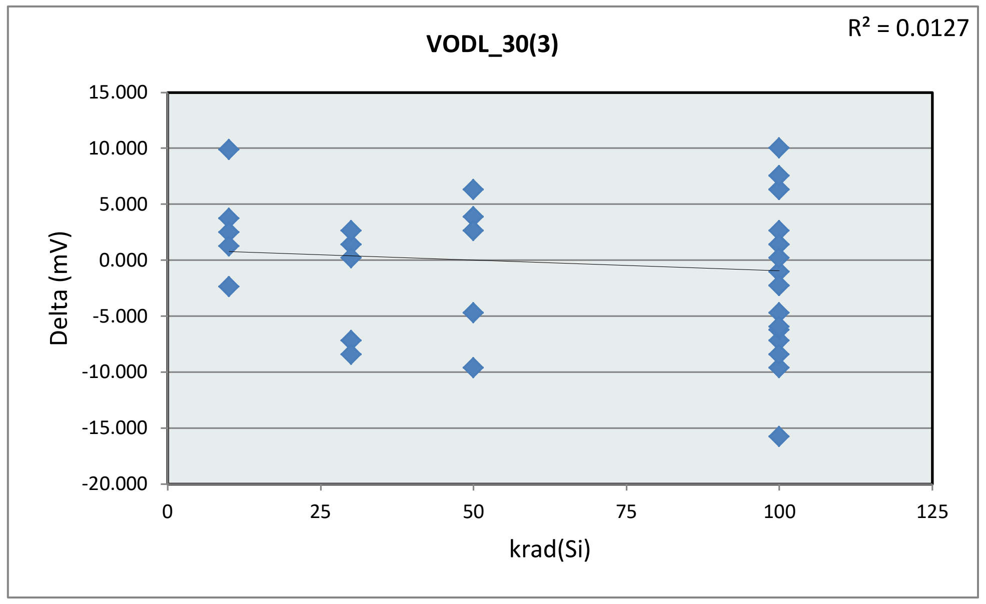
	VODH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	364.909	360.711	365.621	360.713
Average	368.087	367.092	370.284	366.354
Max	369.798	375.440	376.667	371.761
UL	430.000	430.000	430.000	430.000



HDR UnBiased TID Report
SN55LVCP22A-SP

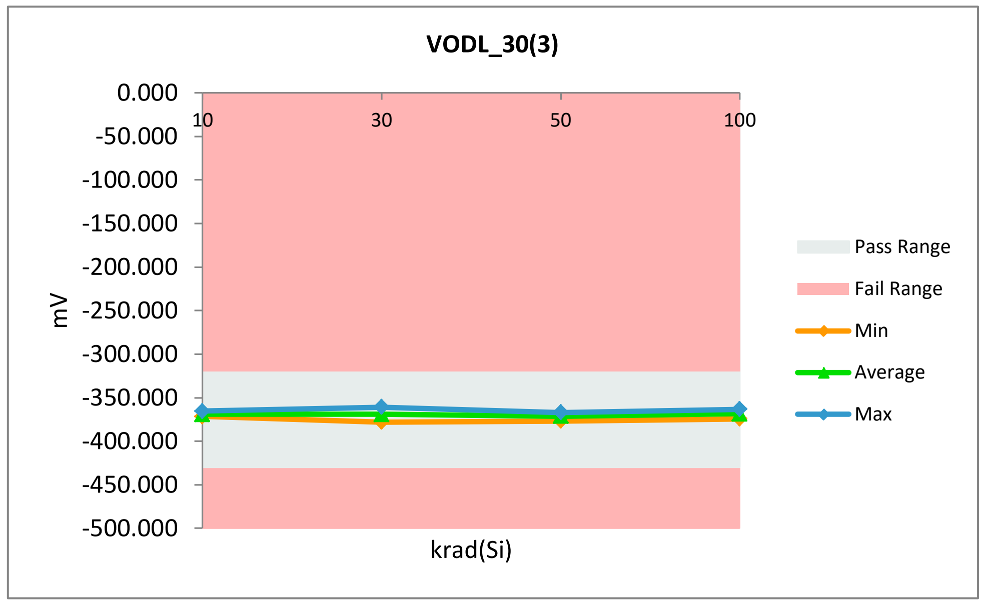
	VODL_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-364.256	-367.996	3.740
10	7	-367.938	-365.556	-2.382
10	8	-360.576	-370.440	9.864
10	9	-367.939	-370.440	2.501
10	10	-370.392	-371.660	1.268
30	6	-369.251	-370.660	1.409
30	7	-375.383	-378.018	2.635
30	8	-368.022	-360.842	-7.180
30	9	-368.024	-368.204	0.180
30	10	-376.613	-368.206	-8.407
50	16	-365.566	-369.433	3.867
50	17	-374.156	-369.431	-4.725
50	18	-376.611	-366.975	-9.636
50	19	-371.701	-374.336	2.635
50	20	-370.479	-376.791	6.312
100	B043	-371.703	-364.526	-7.177
100	B044	-369.250	-366.976	-2.274
100	B045	-364.342	-363.295	-1.047
100	B046	-366.794	-373.111	6.317
100	B047	-363.111	-369.431	6.320
100	B048	-374.156	-364.526	-9.630
100	B049	-372.930	-374.334	1.404
100	B050	-371.702	-366.975	-4.727
100	B051	-372.931	-364.520	-8.411
100	B052	-366.795	-374.336	7.541
100	B053	-363.112	-373.111	9.999
100	B054	-374.156	-373.110	-1.046
100	B055	-370.475	-373.112	2.637
100	B056	-369.251	-366.978	-2.273
100	B057	-365.571	-363.294	-2.277
100	B058	-366.793	-373.109	6.316
100	B059	-363.113	-370.657	7.544
100	B060	-368.024	-369.433	1.409
100	B061	-380.293	-364.527	-15.766
100	B062	-372.929	-366.714	-6.215
100	B063	-369.248	-363.295	-5.953
100	B064	-368.021	-368.207	0.186
	Max	-360.576	-360.842	9.999
	Average	-369.503	-369.096	-0.407
	Min	-380.293	-378.018	-15.766
	Std Dev	4.387	4.115	6.121



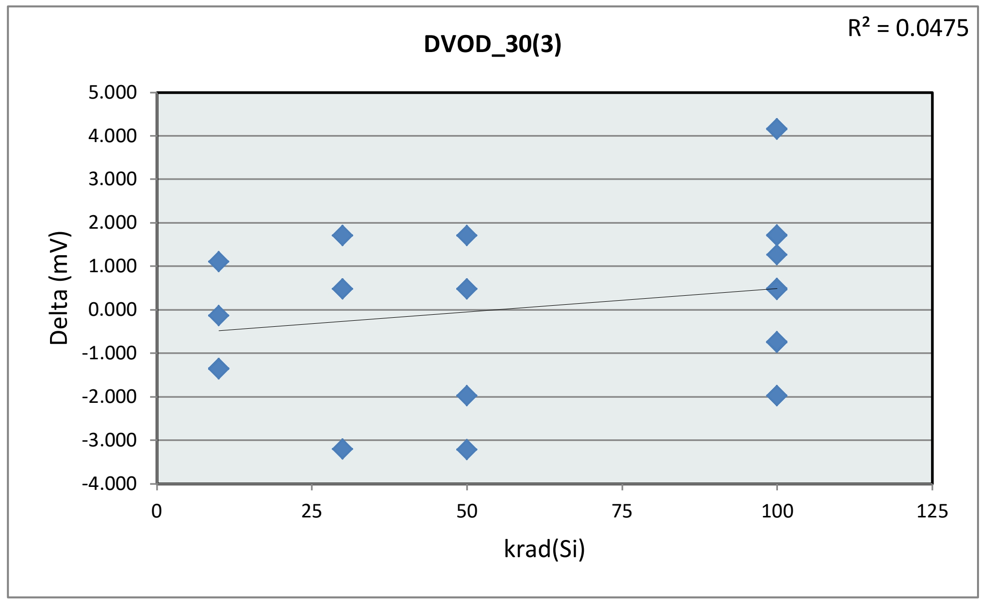
	VODL_30(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-371.660	-378.018	-376.791	-374.336
Average	-369.218	-369.186	-371.393	-368.526
Max	-365.556	-360.842	-366.975	-363.294
UL	-320.000	-320.000	-320.000	-320.000

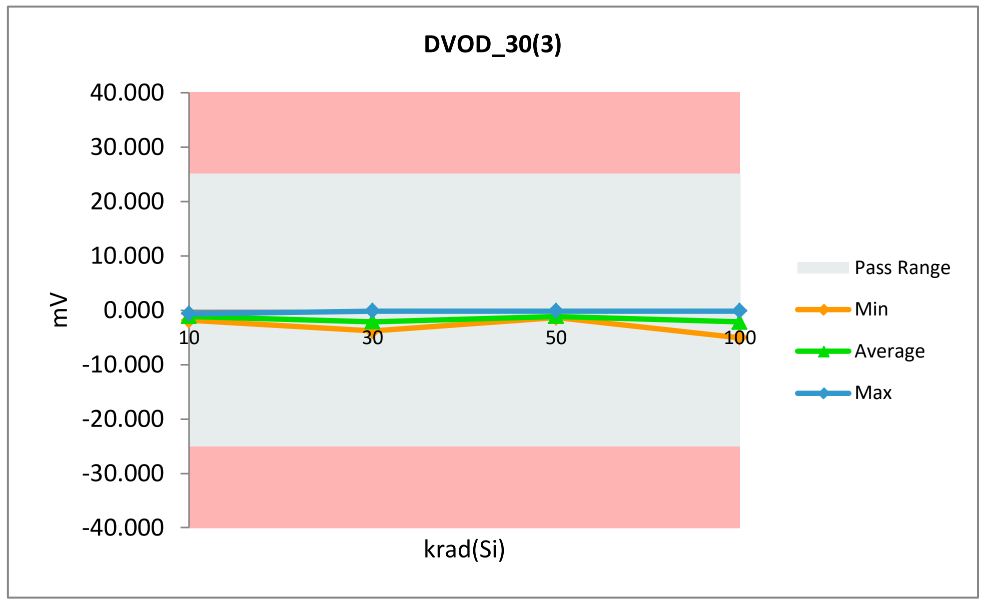


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-1.995	-0.640	-1.355
10	7	-1.997	-0.647	-1.350
10	8	-1.999	-1.865	-0.134
10	9	0.455	-0.642	1.098
10	10	-3.222	-1.862	-1.360
30	6	-0.882	-1.360	0.478
30	7	-0.874	-2.578	1.704
30	8	-3.334	-0.131	-3.203
30	9	-2.110	-3.812	1.702
30	10	-2.106	-2.588	0.482
50	16	-0.877	-1.360	0.483
50	17	-0.874	-1.355	0.481
50	18	0.353	-1.354	1.707
50	19	-3.329	-1.350	-1.979
50	20	-3.338	-0.124	-3.214
100	B043	-2.104	-2.591	0.487
100	B044	-2.107	-1.355	-0.752
100	B045	-3.339	-1.355	-1.984
100	B046	-0.877	-2.581	1.704
100	B047	0.352	-3.812	4.164
100	B048	-3.328	-2.590	-0.738
100	B049	-2.104	-2.573	0.469
100	B050	0.351	-0.127	0.479
100	B051	-0.879	-1.352	0.473
100	B052	-0.881	-5.032	4.151
100	B053	-3.332	-2.580	-0.752
100	B054	-2.101	-2.580	0.479
100	B055	-3.331	-1.356	-1.975
100	B056	-2.109	-1.359	-0.750
100	B057	-2.114	-2.582	0.468
100	B058	-2.104	-1.350	-0.754
100	B059	0.348	-3.808	4.156
100	B060	-0.884	-2.587	1.703
100	B061	-2.103	-1.366	-0.737
100	B062	-2.103	-3.366	1.263
100	B063	-2.104	-0.129	-1.975
100	B064	0.350	-1.363	1.713
	Max	0.455	-0.124	4.164
	Average	-1.693	-1.877	0.185
	Min	-3.339	-5.032	-3.214
	Std Dev	1.228	1.163	1.812

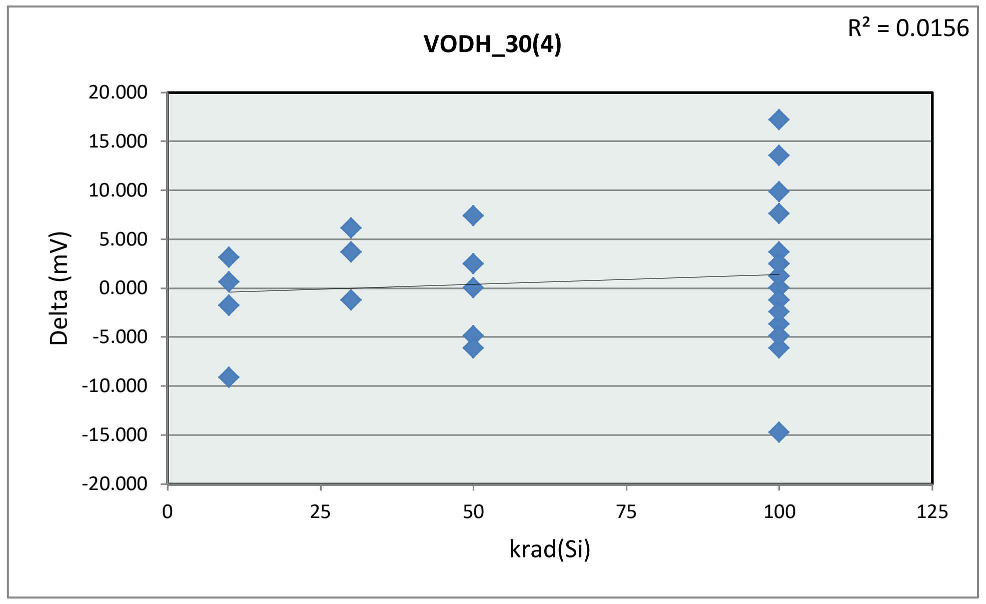


	DVOD_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-1.865	-3.812	-1.360	-5.032
Average	-1.131	-2.094	-1.109	-2.172
Max	-0.640	-0.131	-0.124	-0.127
UL	25.000	25.000	25.000	25.000

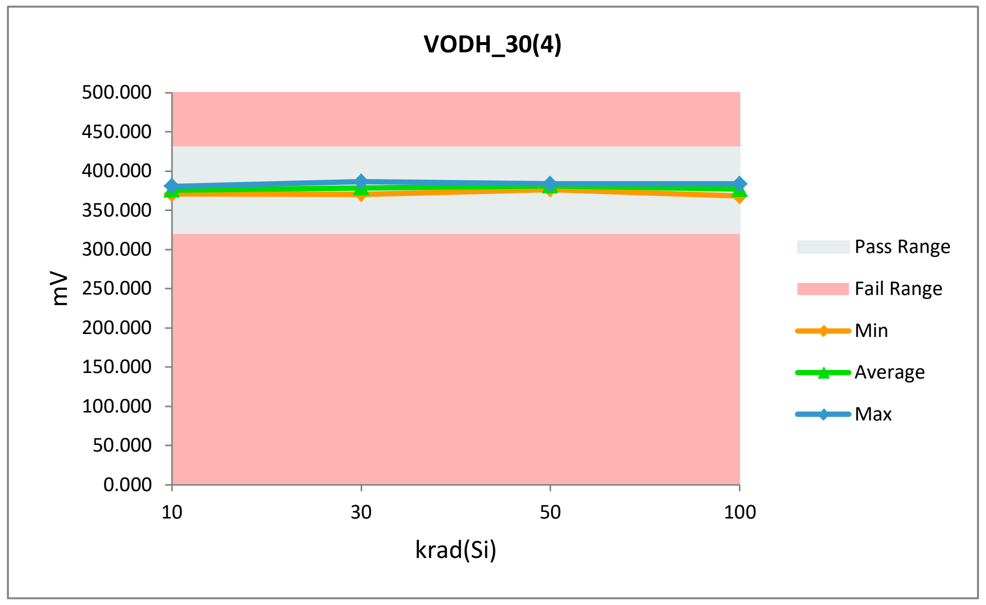


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	371.415	370.754	0.661
10	7	376.322	373.187	3.135
10	8	367.730	376.860	-9.130
10	9	376.320	378.074	-1.754
10	10	378.781	380.533	-1.752
30	6	380.057	381.266	-1.209
30	7	384.972	386.175	-1.203
30	8	373.921	370.219	3.702
30	9	380.062	373.902	6.160
30	10	383.737	380.038	3.699
50	16	380.059	380.038	0.021
50	17	383.741	376.356	7.385
50	18	383.743	381.266	2.477
50	19	378.835	383.720	-4.885
50	20	377.602	383.720	-6.118
100	B043	380.061	370.219	9.842
100	B044	378.829	377.584	1.245
100	B045	369.005	370.219	-1.214
100	B046	380.053	380.038	0.015
100	B047	377.597	378.811	-1.214
100	B048	381.286	367.765	13.521
100	B049	384.973	382.493	2.480
100	B050	381.283	380.038	1.245
100	B051	380.064	377.583	2.481
100	B052	377.606	381.266	-3.660
100	B053	369.012	383.721	-14.709
100	B054	383.746	380.038	3.708
100	B055	381.286	380.038	1.248
100	B056	377.604	376.356	1.248
100	B057	370.234	368.992	1.242
100	B058	376.380	382.493	-6.113
100	B059	375.144	380.038	-4.894
100	B060	376.377	377.584	-1.207
100	B061	387.427	370.219	17.208
100	B062	381.290	373.694	7.596
100	B063	378.833	376.356	2.477
100	B064	373.920	376.356	-2.436
	Max	387.427	386.175	17.208
	Average	378.360	377.514	0.846
	Min	367.730	367.765	-14.709
	Std Dev	4.739	4.762	5.865

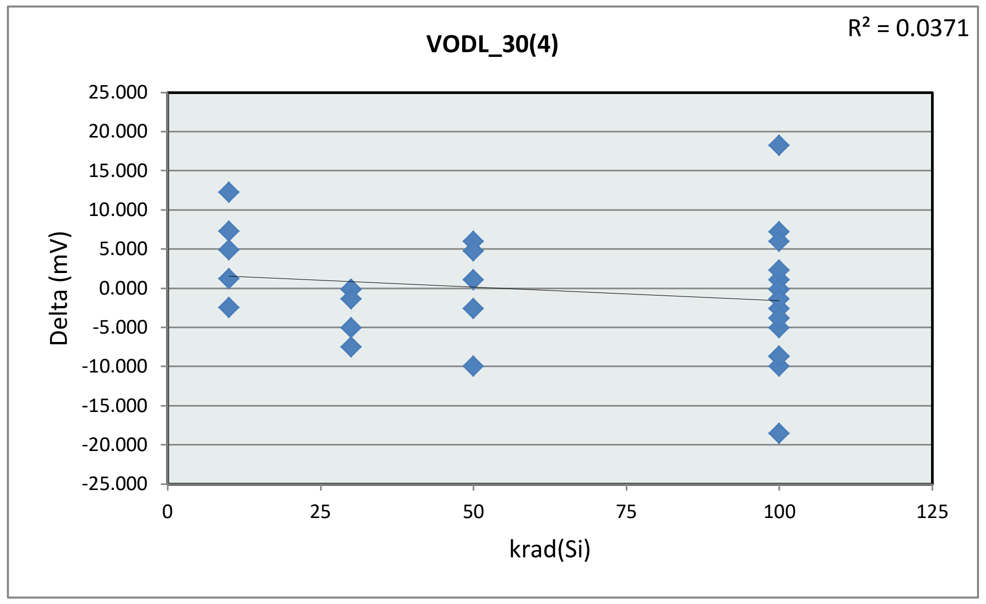


	VODH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	370.754	370.219	376.356	367.765
Average	375.882	378.320	381.020	376.905
Max	380.533	386.175	383.720	383.721
UL	430.000	430.000	430.000	430.000

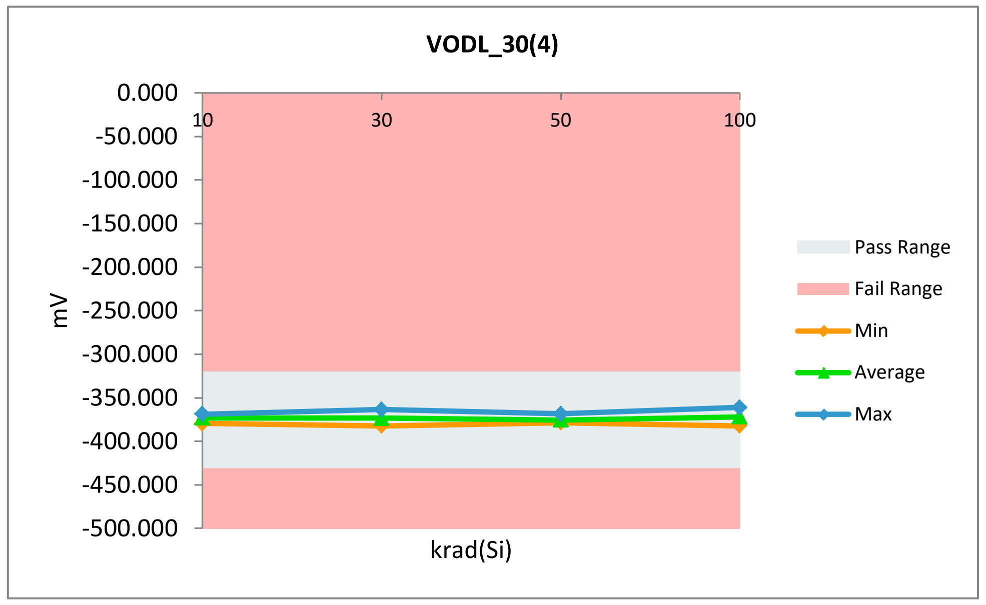


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-365.001	-369.864	4.863
10	7	-371.140	-368.672	-2.468
10	8	-361.323	-373.555	12.232
10	9	-372.370	-373.563	1.193
10	10	-372.364	-379.658	7.294
30	6	-376.173	-376.012	-0.161
30	7	-382.306	-382.148	-0.158
30	8	-368.805	-363.738	-5.067
30	9	-376.168	-368.647	-7.521
30	10	-377.404	-376.011	-1.393
50	16	-376.170	-377.239	1.069
50	17	-378.627	-368.647	-9.980
50	18	-378.626	-376.011	-2.615
50	19	-372.484	-378.466	5.982
50	20	-372.489	-377.239	4.750
100	B043	-373.714	-364.965	-8.749
100	B044	-374.945	-371.102	-3.843
100	B045	-366.355	-366.193	-0.162
100	B046	-376.177	-373.557	-2.620
100	B047	-373.722	-374.784	1.062
100	B048	-374.945	-364.965	-9.980
100	B049	-382.306	-377.239	-5.067
100	B050	-374.947	-376.012	1.065
100	B051	-376.166	-372.330	-3.836
100	B052	-372.486	-373.557	1.071
100	B053	-363.894	-382.148	18.254
100	B054	-377.395	-374.784	-2.611
100	B055	-376.171	-376.011	-0.160
100	B056	-372.487	-372.329	-0.158
100	B057	-362.671	-361.283	-1.388
100	B058	-370.029	-377.239	7.210
100	B059	-370.037	-376.011	5.974
100	B060	-370.032	-372.329	2.297
100	B061	-381.080	-362.511	-18.569
100	B062	-377.395	-368.739	-8.656
100	B063	-373.714	-369.875	-3.839
100	B064	-367.579	-369.875	2.296
	Max	-361.323	-361.283	18.254
	Average	-373.235	-372.630	-0.605
	Min	-382.306	-382.148	-18.569
	Std Dev	5.120	5.239	6.639

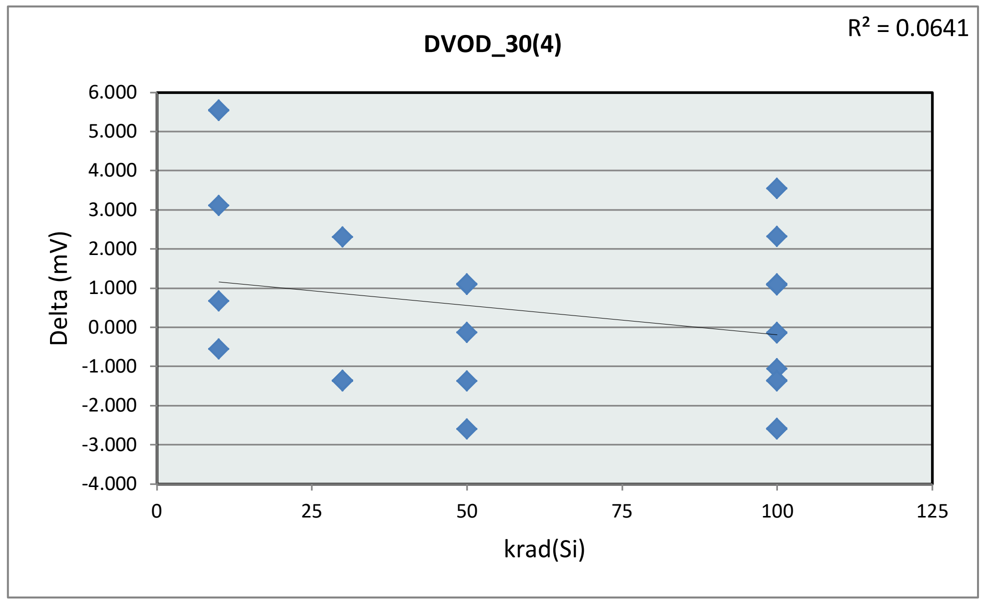


	VODL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-379.658	-382.148	-378.466	-382.148
Average	-373.062	-373.311	-375.520	-371.720
Max	-368.672	-363.738	-368.647	-361.283
UL	-320.000	-320.000	-320.000	-320.000

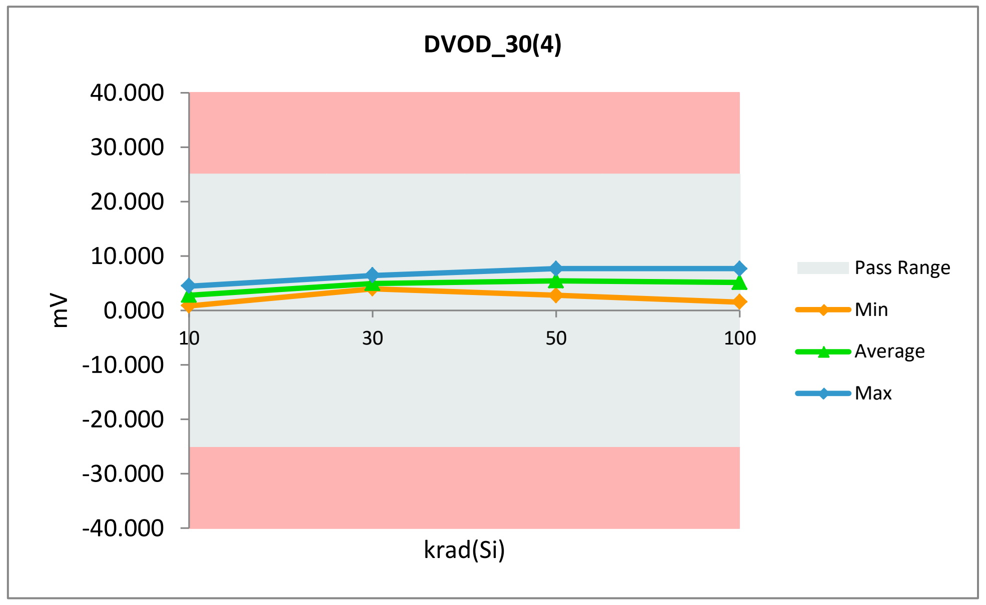


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	6.414	0.890	5.524
10	7	5.182	4.515	0.667
10	8	6.407	3.305	3.102
10	9	3.950	4.511	-0.561
10	10	6.418	0.875	5.543
30	6	3.885	5.254	-1.369
30	7	2.666	4.027	-1.361
30	8	5.116	6.482	-1.366
30	9	3.894	5.254	-1.360
30	10	6.333	4.027	2.306
50	16	3.889	2.800	1.089
50	17	5.114	7.709	-2.595
50	18	5.117	5.254	-0.137
50	19	6.352	5.254	1.098
50	20	5.113	6.482	-1.369
100	B043	6.346	5.254	1.092
100	B044	3.884	6.481	-2.597
100	B045	2.651	4.027	-1.376
100	B046	3.877	6.482	-2.605
100	B047	3.875	4.027	-0.152
100	B048	6.341	2.799	3.542
100	B049	2.667	5.254	-2.587
100	B050	6.336	4.026	2.310
100	B051	3.898	5.254	-1.356
100	B052	5.120	7.709	-2.589
100	B053	5.118	1.572	3.546
100	B054	6.351	5.254	1.097
100	B055	5.115	4.027	1.088
100	B056	5.117	4.027	1.090
100	B057	7.564	7.709	-0.145
100	B058	6.351	5.254	1.097
100	B059	5.107	4.027	1.080
100	B060	6.344	5.254	1.090
100	B061	6.347	7.709	-1.362
100	B062	3.895	4.955	-1.060
100	B063	5.118	6.481	-1.363
100	B064	6.340	6.482	-0.142
	Max	7.564	7.709	5.543
	Average	5.125	4.884	0.241
	Min	2.651	0.875	-2.605
	Std Dev	1.265	1.740	2.158



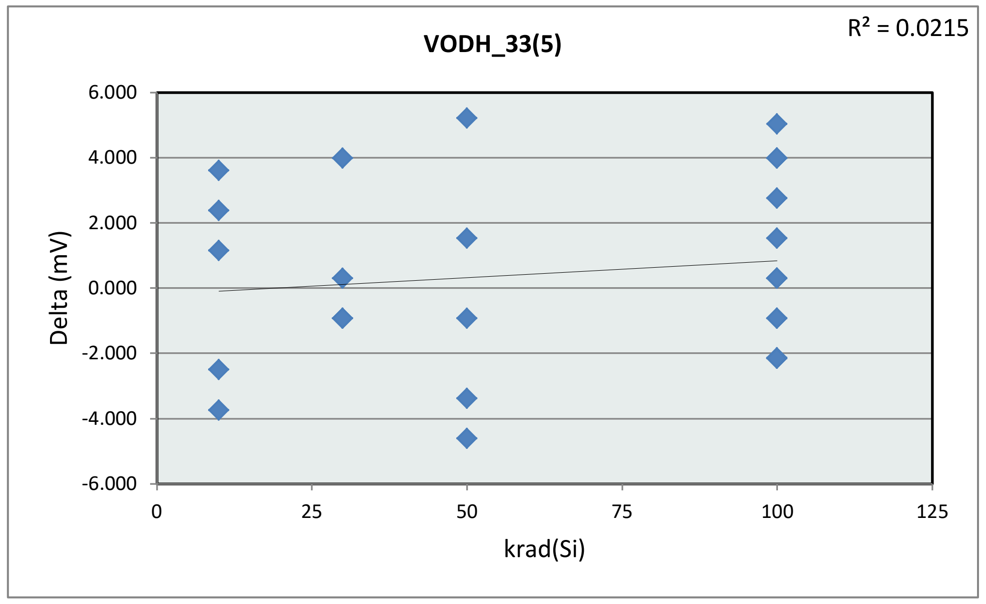
	DVOD_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.875	4.027	2.800	1.572
Average	2.819	5.009	5.500	5.185
Max	4.515	6.482	7.709	7.709
UL	25.000	25.000	25.000	25.000



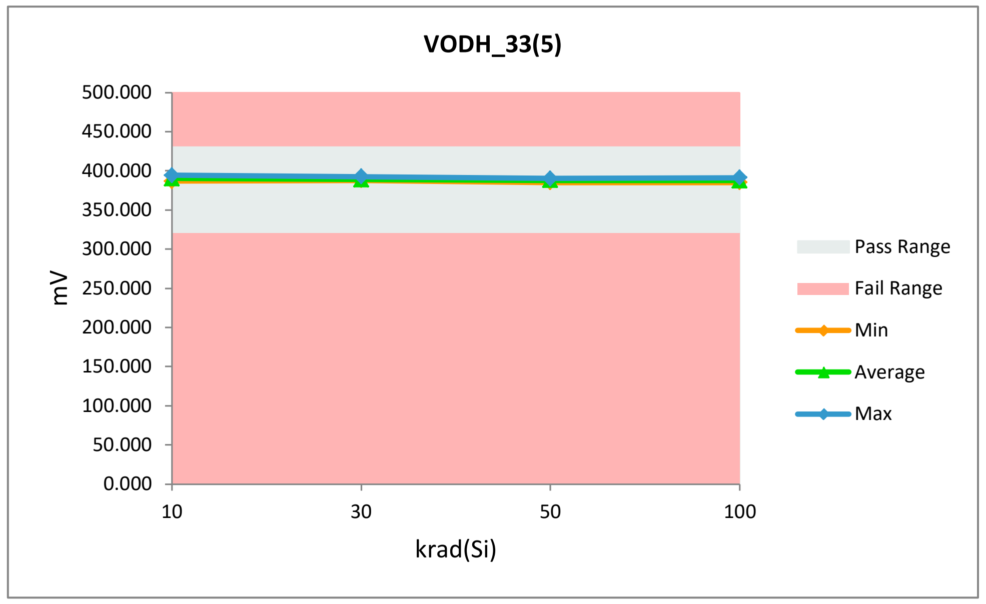
HDR UnBiased TID Report
SN55LVCP22A-SP

	VODH_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	389.258	388.112	1.146
10	7	391.711	394.217	-2.506
10	8	389.256	392.996	-3.740
10	9	391.710	388.111	3.599
10	10	389.258	386.889	2.369
30	6	391.683	392.609	-0.926
30	7	386.777	387.705	-0.928
30	8	388.002	387.703	0.299
30	9	386.774	387.702	-0.928
30	10	392.911	388.927	3.984
50	16	383.094	387.701	-4.607
50	17	386.777	390.158	-3.381
50	18	390.459	385.249	5.210
50	19	386.778	387.705	-0.927
50	20	390.455	388.932	1.523
100	B043	388.004	387.699	0.305
100	B044	388.002	388.930	-0.928
100	B045	389.228	385.249	3.979
100	B046	385.549	387.704	-2.155
100	B047	388.005	387.702	0.303
100	B048	386.778	388.927	-2.149
100	B049	386.776	388.934	-2.158
100	B050	386.776	385.250	1.526
100	B051	391.685	387.705	3.980
100	B052	389.229	387.705	1.524
100	B053	388.004	385.249	2.755
100	B054	386.778	386.477	0.301
100	B055	390.459	391.384	-0.925
100	B056	386.774	388.929	-2.155
100	B057	390.454	386.477	3.977
100	B058	385.550	385.251	0.299
100	B059	388.003	388.931	-0.928
100	B060	389.227	386.474	2.753
100	B061	390.458	390.153	0.305
100	B062	390.459	385.430	5.029
100	B063	388.004	387.703	0.301
100	B064	391.685	387.699	3.986
	Max	392.911	394.217	5.210
	Average	388.670	388.126	0.544
	Min	383.094	385.249	-4.607
	Std Dev	2.178	2.139	2.587



	VODH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	386.889	387.702	385.249	385.249
Average	390.065	388.929	387.949	387.544
Max	394.217	392.609	390.158	391.384
UL	430.000	430.000	430.000	430.000



HDR UnBiased TID Report
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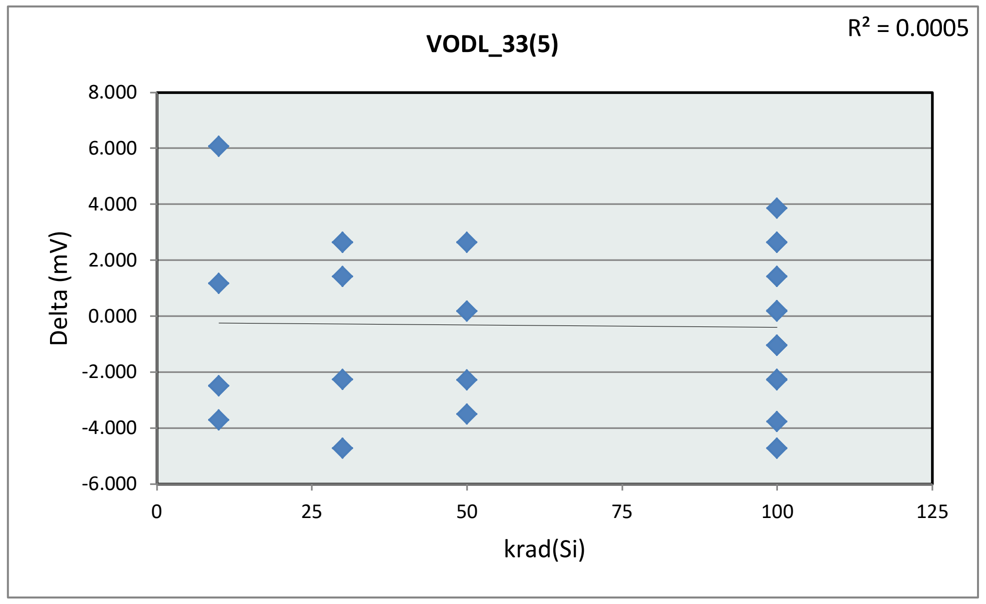
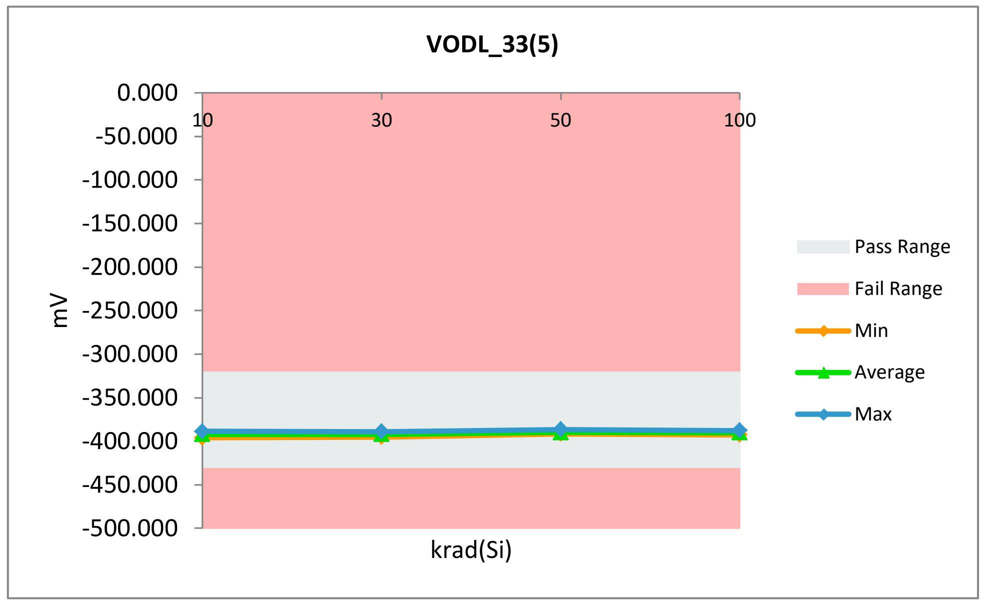
		VODL_33(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-392.484	-389.992	-2.492
10	7	-393.712	-394.881	1.169
10	8	-390.031	-396.101	6.070
10	9	-392.486	-389.993	-2.493
10	10	-392.484	-388.772	-3.712
30	6	-392.574	-395.209	2.635
30	7	-390.117	-391.523	1.406
30	8	-391.346	-389.071	-2.275
30	9	-390.120	-392.752	2.632
30	10	-396.256	-391.527	-4.729
50	16	-386.435	-389.073	2.638
50	17	-391.344	-391.525	0.181
50	18	-390.117	-386.615	-3.502
50	19	-391.343	-391.523	0.180
50	20	-393.802	-391.523	-2.279
100	B043	-391.345	-390.302	-1.043
100	B044	-391.346	-389.071	-2.275
100	B045	-391.348	-389.070	-2.278
100	B046	-388.890	-392.751	3.861
100	B047	-388.889	-390.299	1.410
100	B048	-392.571	-392.755	0.184
100	B049	-387.663	-390.294	2.631
100	B050	-388.890	-387.842	-1.048
100	B051	-392.573	-387.841	-4.732
100	B052	-390.119	-392.750	2.631
100	B053	-390.117	-389.070	-1.047
100	B054	-388.889	-389.070	0.181
100	B055	-390.117	-392.752	2.635
100	B056	-388.893	-390.299	1.406
100	B057	-391.349	-390.297	-1.052
100	B058	-388.889	-389.068	0.179
100	B059	-388.891	-391.524	2.633
100	B060	-391.348	-389.073	-2.275
100	B061	-396.254	-391.530	-4.724
100	B062	-392.572	-388.804	-3.768
100	B063	-390.117	-389.071	-1.046
100	B064	-392.572	-391.528	-1.044
	Max	-386.435	-386.615	6.070
	Average	-391.035	-390.679	-0.355
	Min	-396.256	-396.101	-4.732
	Std Dev	2.107	2.105	2.663

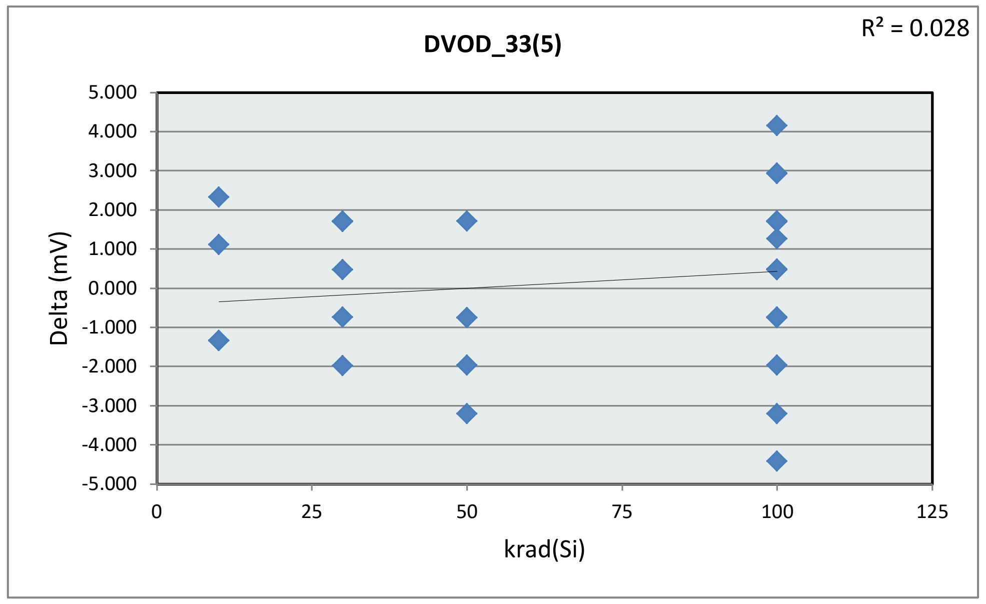


	VODL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-396.101	-395.209	-391.525	-392.755
Average	-391.948	-392.016	-390.052	-390.230
Max	-388.772	-389.071	-386.615	-387.841
UL	-320.000	-320.000	-320.000	-320.000

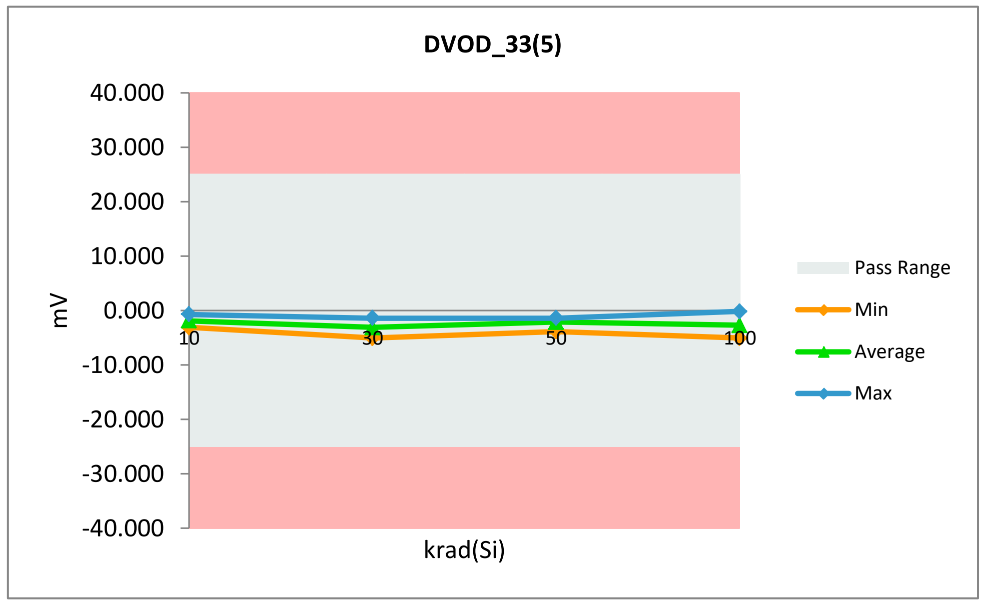


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-3.226	-1.880	-1.346
10	7	-2.001	-0.664	-1.337
10	8	-0.775	-3.105	2.330
10	9	-0.776	-1.883	1.107
10	10	-3.226	-1.882	-1.344
30	6	-0.891	-2.599	1.708
30	7	-3.340	-3.818	0.478
30	8	-3.343	-1.368	-1.975
30	9	-3.347	-5.050	1.703
30	10	-3.344	-2.600	-0.744
50	16	-3.341	-1.372	-1.969
50	17	-4.566	-1.367	-3.199
50	18	0.342	-1.366	1.708
50	19	-4.566	-3.818	-0.748
50	20	-3.347	-2.592	-0.755
100	B043	-3.341	-2.602	-0.739
100	B044	-3.344	-0.141	-3.203
100	B045	-2.120	-3.820	1.700
100	B046	-3.341	-5.048	1.707
100	B047	-0.884	-2.597	1.713
100	B048	-5.793	-3.828	-1.965
100	B049	-0.886	-1.360	0.474
100	B050	-2.114	-2.592	0.478
100	B051	-0.888	-0.136	-0.752
100	B052	-0.890	-5.045	4.155
100	B053	-2.113	-3.820	1.707
100	B054	-2.111	-2.593	0.482
100	B055	0.342	-1.368	1.710
100	B056	-2.118	-1.371	-0.747
100	B057	-0.895	-3.819	2.924
100	B058	-3.340	-3.817	0.477
100	B059	-0.888	-2.592	1.704
100	B060	-2.121	-2.599	0.478
100	B061	-5.796	-1.377	-4.419
100	B062	-2.113	-3.373	1.260
100	B063	-2.113	-1.368	-0.745
100	B064	-0.887	-3.829	2.942
	Max	0.342	-0.136	4.155
	Average	-2.365	-2.553	0.188
	Min	-5.796	-5.050	-4.419
	Std Dev	1.509	1.310	1.900



	DVOD_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-3.105	-5.050	-3.818	-5.048
Average	-1.883	-3.087	-2.103	-2.686
Max	-0.664	-1.368	-1.366	-0.136
UL	25.000	25.000	25.000	25.000



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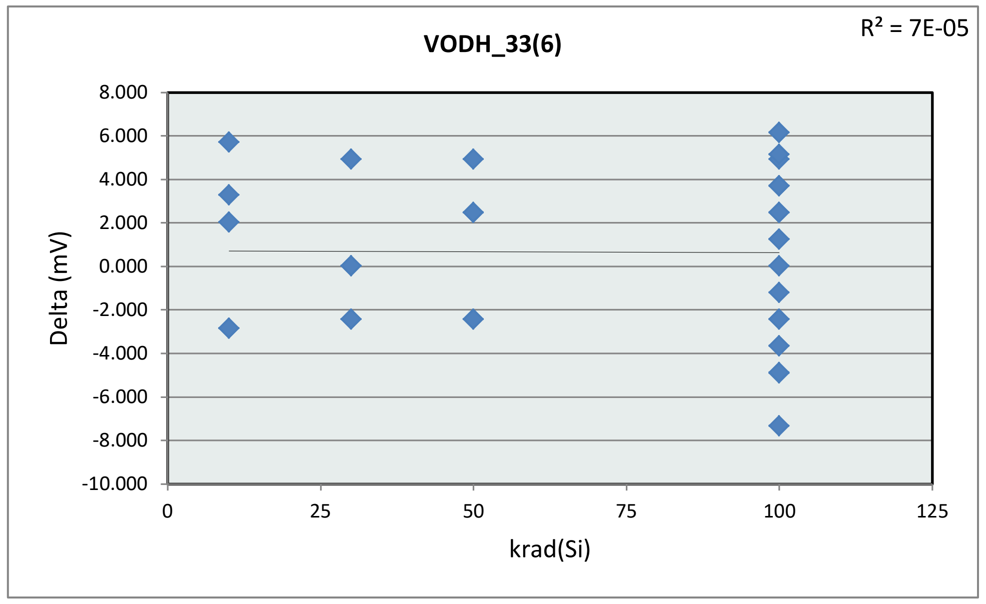
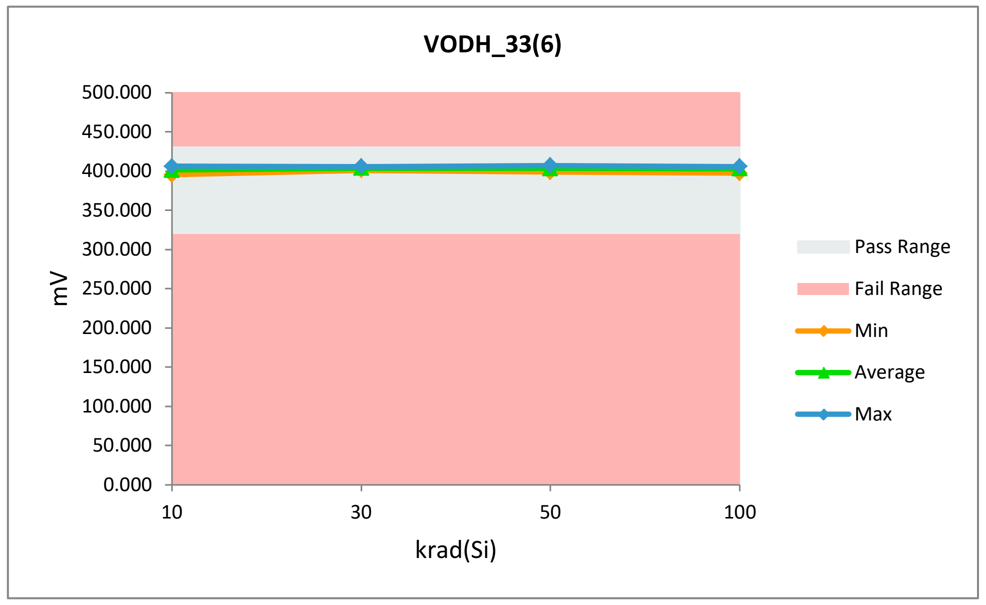
	VODH_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	400.862	395.163	5.699
10	7	403.314	406.155	-2.841
10	8	402.087	404.939	-2.852
10	9	400.856	398.814	2.042
10	10	404.545	401.273	3.272
30	6	403.375	405.812	-2.437
30	7	398.468	400.903	-2.435
30	8	403.378	403.358	0.020
30	9	403.379	403.358	0.021
30	10	409.510	404.585	4.925
50	16	400.921	398.448	2.473
50	17	405.830	403.358	2.472
50	18	405.833	400.903	4.930
50	19	404.609	407.040	-2.431
50	20	404.604	407.040	-2.436
100	B043	404.606	403.358	1.248
100	B044	400.920	404.585	-3.665
100	B045	403.373	399.676	3.697
100	B046	400.915	405.813	-4.898
100	B047	405.825	399.676	6.149
100	B048	404.604	403.358	1.246
100	B049	398.469	405.813	-7.344
100	B050	405.828	402.130	3.698
100	B051	400.926	405.812	-4.886
100	B052	402.151	404.585	-2.434
100	B053	402.151	397.221	4.930
100	B054	403.380	405.812	-2.432
100	B055	404.604	402.131	2.473
100	B056	400.922	402.131	-1.209
100	B057	403.374	402.131	1.243
100	B058	402.154	402.130	0.024
100	B059	405.828	403.358	2.470
100	B060	403.377	400.903	2.474
100	B061	408.288	402.130	6.158
100	B062	407.063	401.912	5.151
100	B063	402.151	405.812	-3.661
100	B064	405.831	402.130	3.701
	Max	409.510	407.040	6.158
	Average	403.468	402.804	0.664
	Min	398.468	395.163	-7.344
	Std Dev	2.465	2.781	3.591



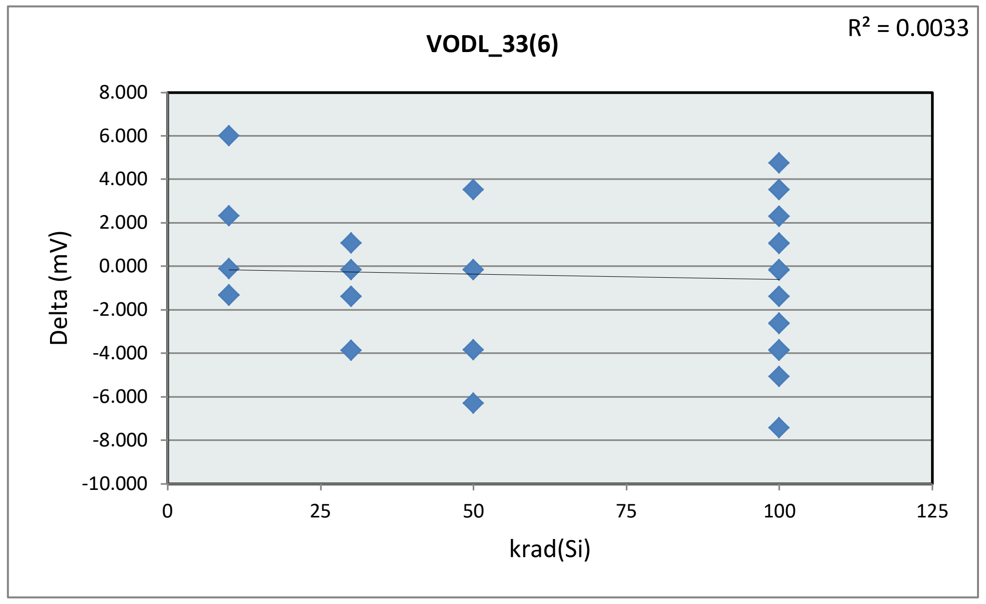
	VODH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	395.163	400.903	398.448	397.221
Average	401.269	403.603	403.358	402.846
Max	406.155	405.812	407.040	405.813
UL	430.000	430.000	430.000	430.000



HDR UnBiased TID Report
SN55LVCP22A-SP

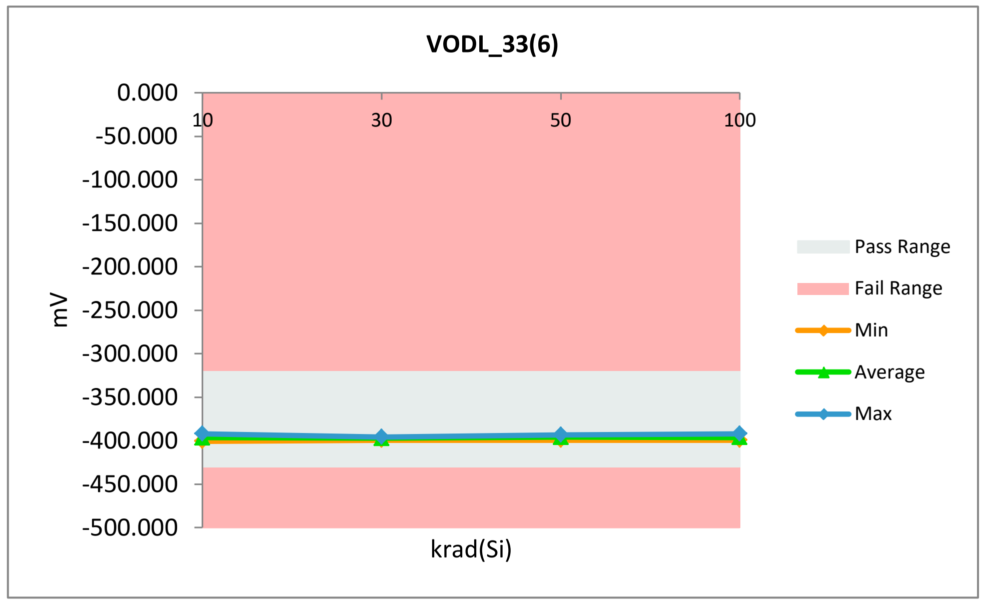
	VODL_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-392.012	-391.894	-0.118
10	7	-398.152	-400.479	2.327
10	8	-393.242	-399.250	6.008
10	9	-394.474	-393.153	-1.321
10	10	-399.376	-398.027	-1.349
30	6	-399.505	-399.332	-0.173
30	7	-394.591	-395.649	1.058
30	8	-397.047	-395.649	-1.398
30	9	-398.273	-396.877	-1.396
30	10	-401.964	-398.104	-3.860
50	16	-394.593	-394.422	-0.171
50	17	-399.505	-393.195	-6.310
50	18	-398.275	-394.422	-3.853
50	19	-395.816	-399.332	3.516
50	20	-398.277	-398.104	-0.173
100	B043	-397.047	-395.650	-1.397
100	B044	-395.823	-398.104	2.281
100	B045	-398.280	-394.422	-3.858
100	B046	-395.827	-396.877	1.050
100	B047	-399.510	-395.650	-3.860
100	B048	-397.049	-399.332	2.283
100	B049	-393.363	-395.649	2.286
100	B050	-399.508	-396.877	-2.631
100	B051	-395.816	-399.332	3.516
100	B052	-393.363	-398.104	4.741
100	B053	-395.818	-393.195	-2.623
100	B054	-395.817	-399.332	3.515
100	B055	-399.505	-395.649	-3.856
100	B056	-395.820	-394.422	-1.398
100	B057	-394.596	-394.422	-0.174
100	B058	-394.588	-395.649	1.061
100	B059	-399.507	-399.332	-0.175
100	B060	-394.592	-394.422	-0.170
100	B061	-399.503	-394.422	-5.081
100	B062	-399.500	-392.061	-7.439
100	B063	-395.819	-398.104	2.285
100	B064	-395.821	-395.649	-0.172
	Max	-392.012	-391.894	6.008
	Average	-396.799	-396.339	-0.460
	Min	-401.964	-400.479	-7.439
	Std Dev	2.358	2.334	3.065



	VODL_33(6)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-400.479	-399.332	-399.332	-399.332
Average	-396.561	-397.122	-395.895	-396.212
Max	-391.894	-395.649	-393.195	-392.061
UL	-320.000	-320.000	-320.000	-320.000



HDR UnBiased TID Report
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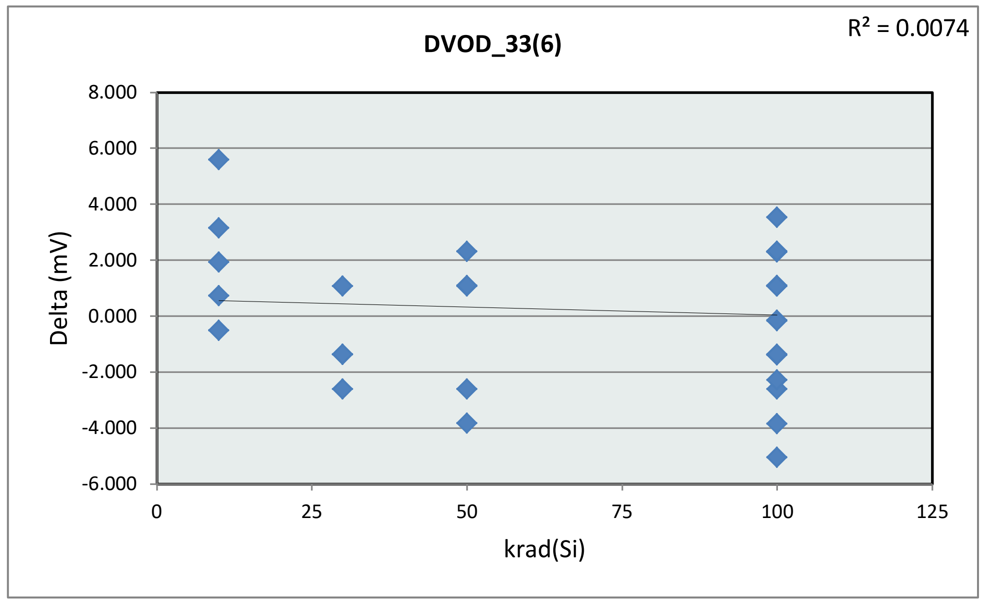
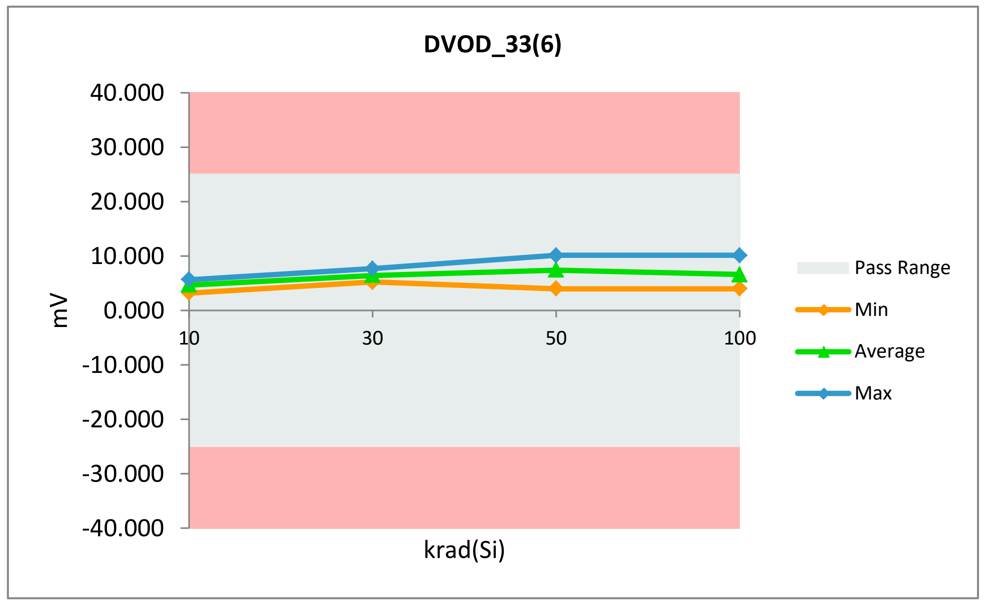
		DVOD_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	8.850	3.269	5.581
10	7	5.162	5.676	-0.514
10	8	8.845	5.689	3.156
10	9	6.383	5.661	0.722
10	10	5.170	3.246	1.924
30	6	3.870	6.481	-2.611
30	7	3.877	5.254	-1.377
30	8	6.331	7.708	-1.377
30	9	5.106	6.481	-1.375
30	10	7.545	6.481	1.064
50	16	6.328	4.026	2.302
50	17	6.325	10.163	-3.838
50	18	7.558	6.481	1.077
50	19	8.793	7.708	1.085
50	20	6.327	8.936	-2.609
100	B043	7.559	7.708	-0.149
100	B044	5.097	6.481	-1.384
100	B045	5.093	5.254	-0.161
100	B046	5.088	8.936	-3.848
100	B047	6.315	4.026	2.289
100	B048	7.554	4.026	3.528
100	B049	5.106	10.163	-5.057
100	B050	6.321	5.253	1.068
100	B051	5.110	6.480	-1.370
100	B052	8.789	6.481	2.308
100	B053	6.333	4.026	2.307
100	B054	7.562	6.481	1.081
100	B055	5.099	6.481	-1.382
100	B056	5.103	7.709	-2.606
100	B057	8.778	7.709	1.069
100	B058	7.567	6.481	1.086
100	B059	6.321	4.026	2.295
100	B060	8.785	6.481	2.304
100	B061	8.785	7.708	1.077
100	B062	7.564	9.852	-2.288
100	B063	6.332	7.708	-1.376
100	B064	10.010	6.481	3.529
	Max	10.010	10.163	5.581
	Average	6.669	6.465	0.203
	Min	3.870	3.246	-5.057
	Std Dev	1.577	1.814	2.381

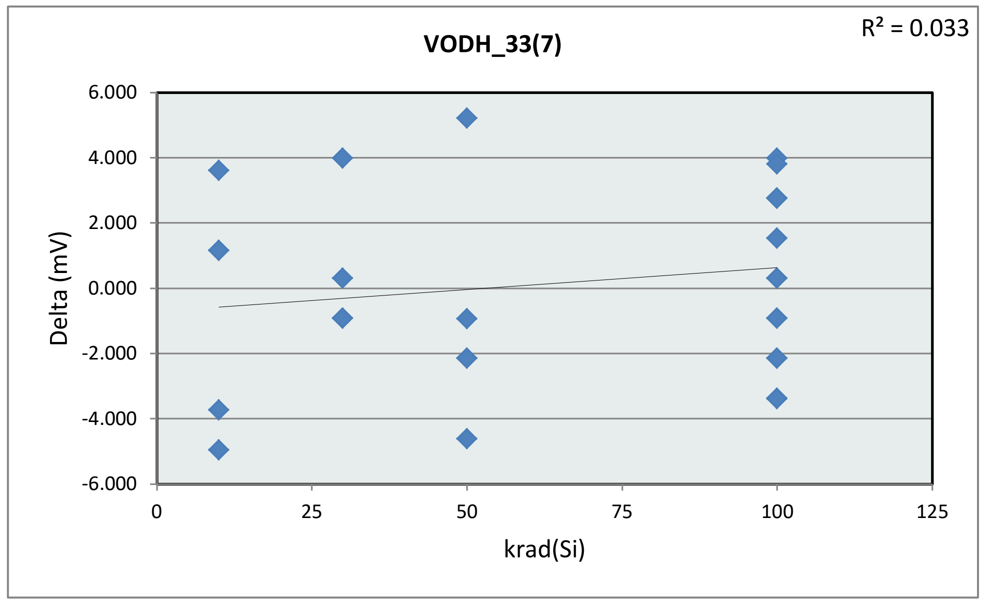


	DVOD_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.246	5.254	4.026	4.026
Average	4.708	6.481	7.463	6.634
Max	5.689	7.708	10.163	10.163
UL	25.000	25.000	25.000	25.000

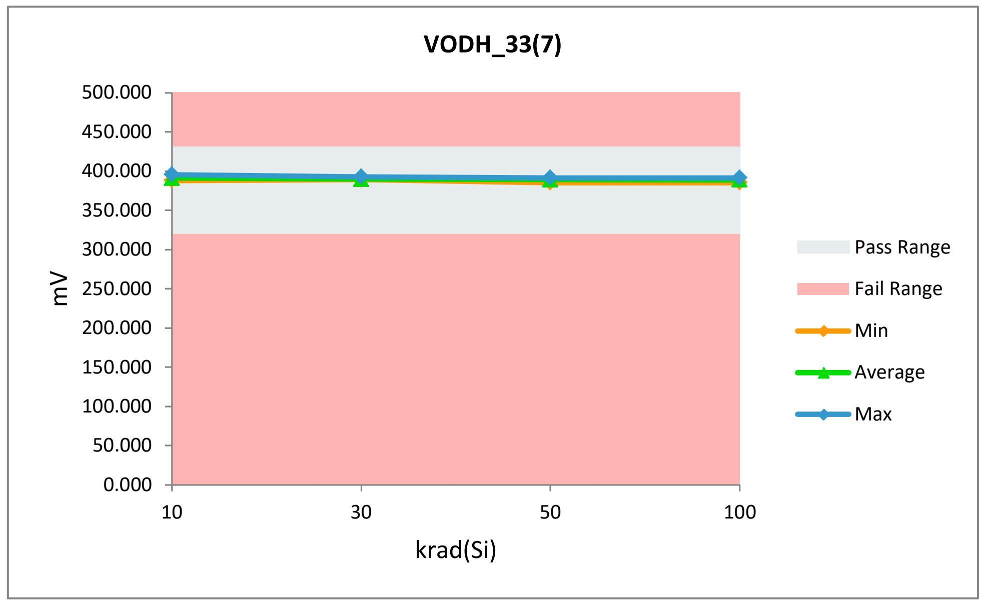


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	389.257	388.109	1.148
10	7	391.710	395.435	-3.725
10	8	389.255	394.215	-4.960
10	9	392.936	389.329	3.607
10	10	389.257	388.109	1.148
30	6	391.682	392.608	-0.926
30	7	388.003	388.930	-0.927
30	8	388.001	388.928	-0.927
30	9	389.227	388.928	0.299
30	10	392.910	388.926	3.984
50	16	384.320	388.927	-4.607
50	17	388.003	390.156	-2.153
50	18	390.458	385.248	5.210
50	19	386.776	388.930	-2.154
50	20	390.454	391.384	-0.930
100	B043	388.002	388.924	-0.922
100	B044	389.228	388.929	0.299
100	B045	389.226	386.475	2.751
100	B046	386.775	388.929	-2.154
100	B047	389.231	387.700	1.531
100	B048	388.004	391.379	-3.375
100	B049	386.775	390.159	-3.384
100	B050	388.002	385.248	2.754
100	B051	391.683	387.703	3.980
100	B052	390.455	388.931	1.524
100	B053	389.230	386.475	2.755
100	B054	388.004	387.702	0.302
100	B055	390.457	391.382	-0.925
100	B056	388.000	390.154	-2.154
100	B057	390.453	387.703	2.750
100	B058	385.548	386.476	-0.928
100	B059	390.456	390.157	0.299
100	B060	389.226	386.472	2.754
100	B061	392.911	390.150	2.761
100	B062	390.457	386.657	3.800
100	B063	388.002	390.155	-2.153
100	B064	392.911	390.152	2.759
	Max	392.936	395.435	5.210
	Average	389.332	389.086	0.246
	Min	384.320	385.248	-4.960
	Std Dev	2.055	2.207	2.670

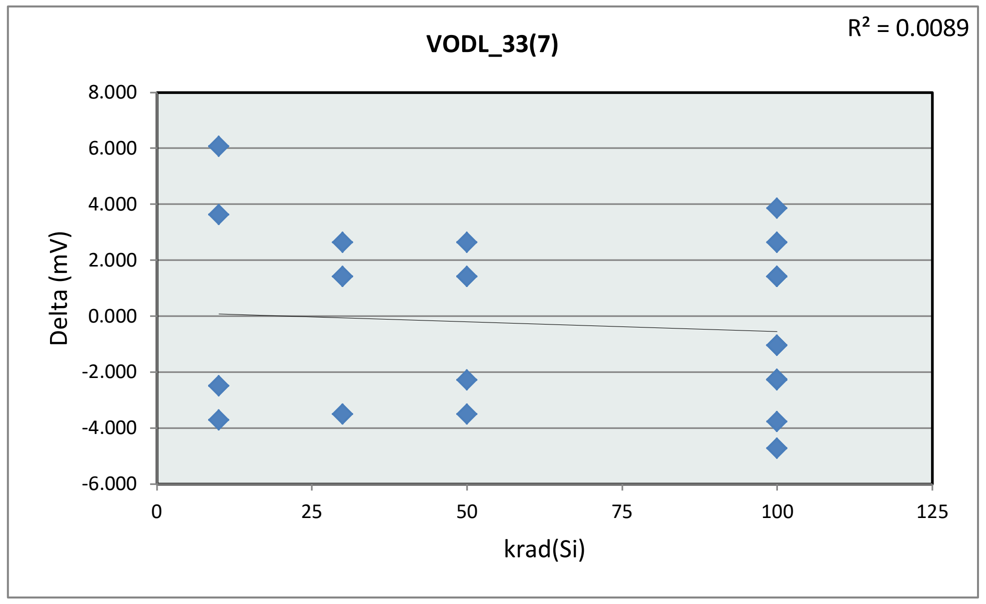


	VODH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	388.109	388.926	385.248	385.248
Average	391.039	389.664	388.929	388.546
Max	395.435	392.608	391.384	391.382
UL	430.000	430.000	430.000	430.000

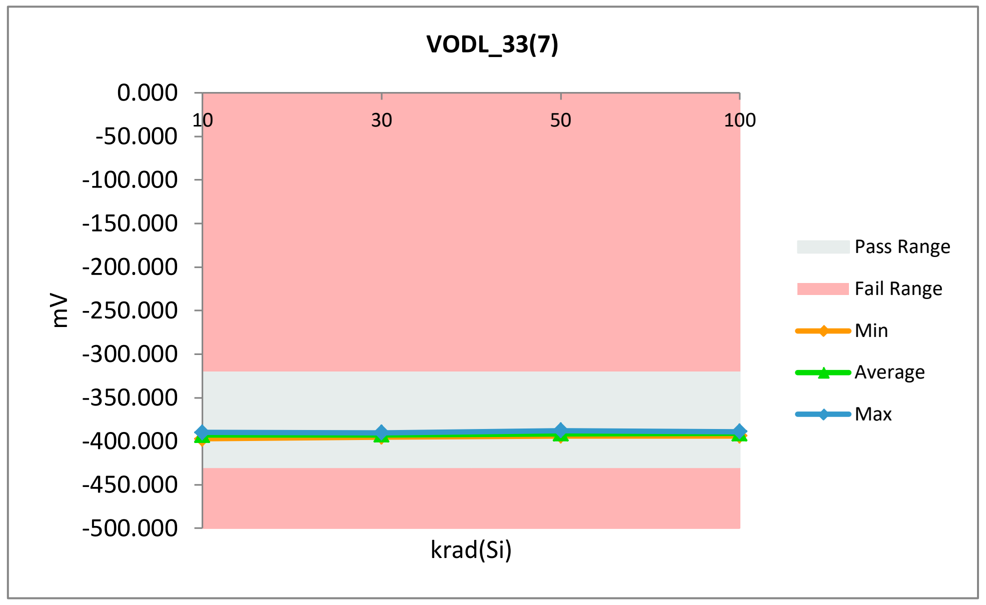


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-392.484	-389.995	-2.489
10	7	-392.485	-396.105	3.620
10	8	-391.259	-397.325	6.066
10	9	-393.714	-391.217	-2.497
10	10	-393.711	-389.996	-3.715
30	6	-393.803	-395.210	1.407
30	7	-390.118	-391.525	1.407
30	8	-393.802	-390.300	-3.502
30	9	-391.349	-393.981	2.632
30	10	-396.257	-392.756	-3.501
50	16	-387.664	-390.302	2.638
50	17	-392.572	-393.981	1.409
50	18	-391.346	-387.844	-3.502
50	19	-391.345	-392.751	1.406
50	20	-395.031	-392.752	-2.279
100	B043	-392.573	-390.303	-2.270
100	B044	-391.347	-390.299	-1.048
100	B045	-393.804	-389.071	-4.733
100	B046	-388.891	-392.753	3.862
100	B047	-388.890	-390.301	1.411
100	B048	-392.572	-393.984	1.412
100	B049	-388.891	-390.296	1.405
100	B050	-390.118	-389.071	-1.047
100	B051	-392.574	-390.297	-2.277
100	B052	-391.347	-393.978	2.631
100	B053	-391.346	-389.072	-2.274
100	B054	-388.890	-390.298	1.408
100	B055	-392.573	-393.981	1.408
100	B056	-390.121	-391.528	1.407
100	B057	-392.578	-391.525	-1.053
100	B058	-390.118	-389.070	-1.048
100	B059	-390.119	-392.753	2.634
100	B060	-392.577	-390.302	-2.275
100	B061	-397.483	-392.759	-4.724
100	B062	-393.800	-390.032	-3.768
100	B063	-392.573	-390.299	-2.274
100	B064	-393.801	-392.757	-1.044
	Max	-387.664	-387.844	6.066
	Average	-391.998	-391.642	-0.356
	Min	-397.483	-397.325	-4.733
	Std Dev	2.114	2.161	2.719

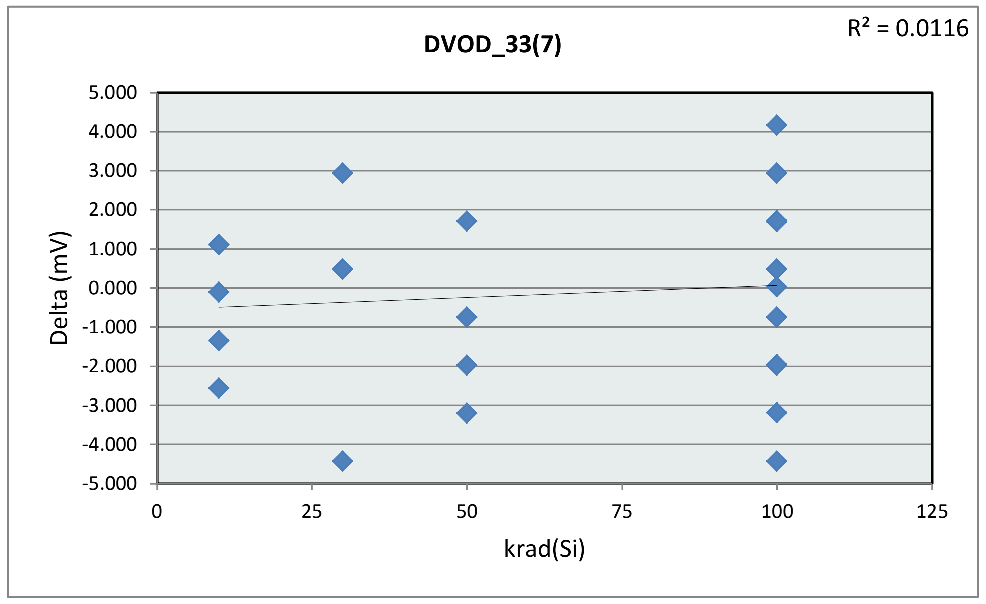


	VODL_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-397.325	-395.210	-393.981	-393.984
Average	-392.928	-392.754	-391.526	-391.124
Max	-389.995	-390.300	-387.844	-389.070
UL	-320.000	-320.000	-320.000	-320.000

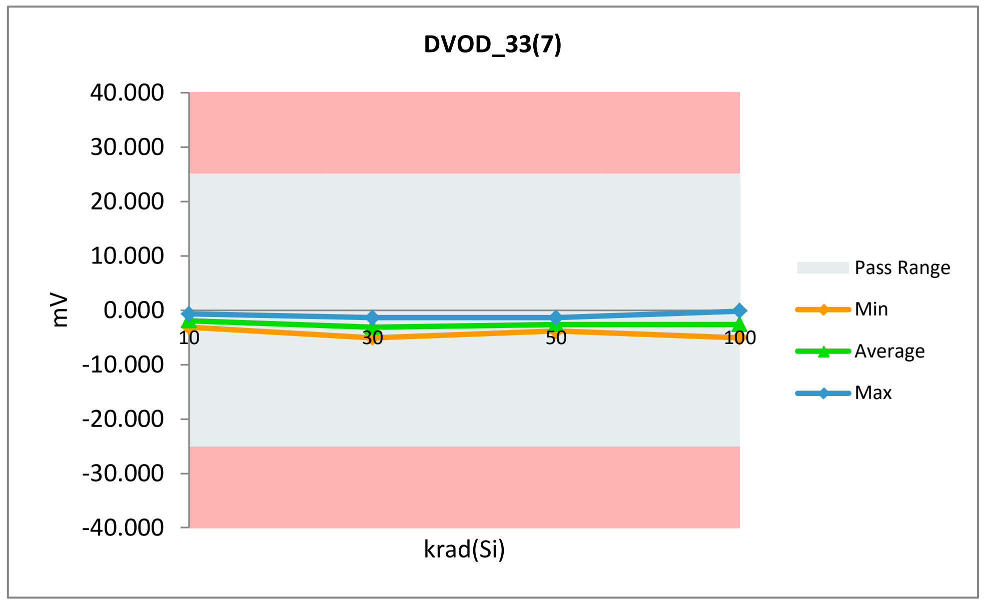


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-3.227	-1.885	-1.342
10	7	-0.775	-0.670	-0.105
10	8	-2.004	-3.110	1.106
10	9	-0.777	-1.888	1.111
10	10	-4.454	-1.887	-2.567
30	6	-2.121	-2.603	0.482
30	7	-2.115	-2.595	0.480
30	8	-5.801	-1.372	-4.429
30	9	-2.122	-5.054	2.932
30	10	-3.347	-3.831	0.484
50	16	-3.344	-1.375	-1.969
50	17	-4.569	-3.825	-0.744
50	18	-0.888	-2.596	1.708
50	19	-4.569	-3.821	-0.748
50	20	-4.576	-1.368	-3.208
100	B043	-4.571	-1.379	-3.192
100	B044	-2.119	-1.371	-0.748
100	B045	-4.577	-2.596	-1.981
100	B046	-2.116	-3.825	1.709
100	B047	0.341	-2.600	2.941
100	B048	-4.569	-2.604	-1.965
100	B049	-2.116	-0.136	-1.980
100	B050	-2.116	-3.823	1.707
100	B051	-0.891	-2.594	1.703
100	B052	-0.892	-5.048	4.156
100	B053	-2.116	-2.597	0.481
100	B054	-0.886	-2.596	1.710
100	B055	-2.116	-2.599	0.483
100	B056	-2.121	-1.374	-0.747
100	B057	-2.125	-3.823	1.698
100	B058	-4.570	-2.594	-1.976
100	B059	0.337	-2.596	2.933
100	B060	-3.351	-3.830	0.479
100	B061	-4.571	-2.608	-1.963
100	B062	-3.343	-3.375	0.032
100	B063	-4.571	-0.144	-4.427
100	B064	-0.890	-2.605	1.715
	Max	0.341	-0.136	4.156
	Average	-2.666	-2.557	-0.109
	Min	-5.801	-5.054	-4.429
	Std Dev	1.604	1.175	2.112

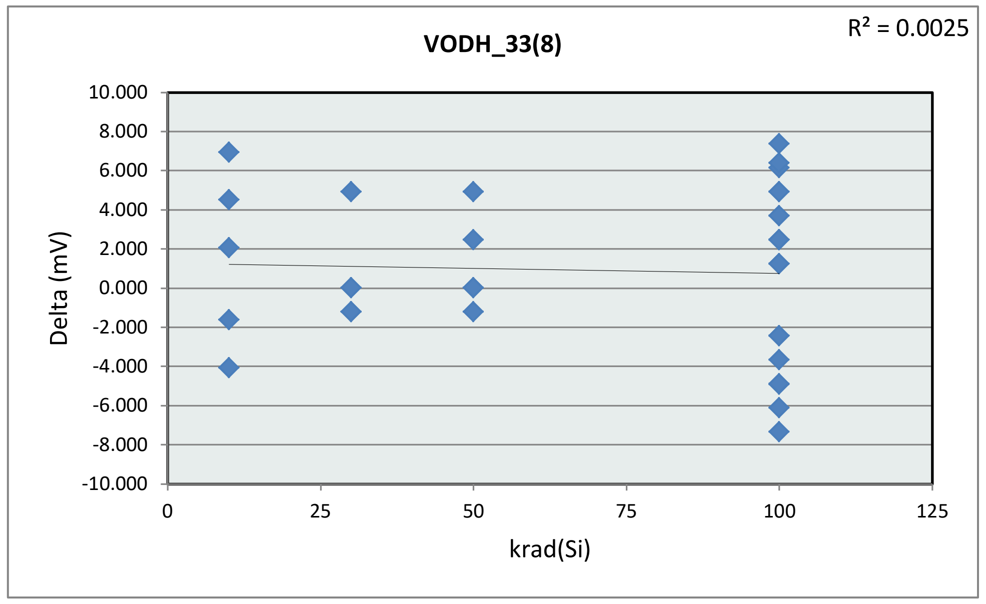


	DVOD_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-3.110	-5.054	-3.825	-5.048
Average	-1.888	-3.091	-2.597	-2.578
Max	-0.670	-1.372	-1.368	-0.136
UL	25.000	25.000	25.000	25.000

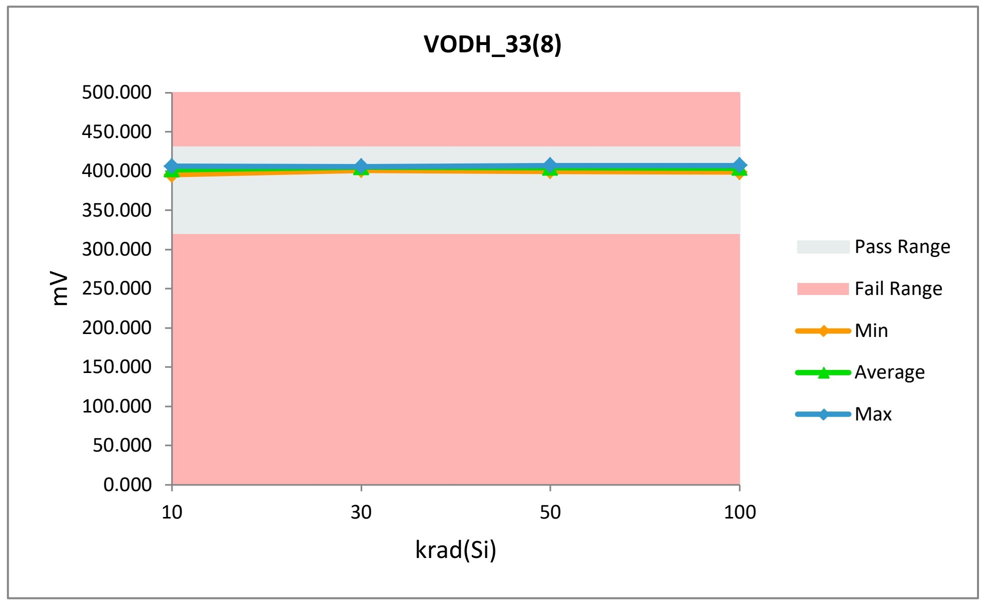


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	402.088	395.154	6.934
10	7	404.539	406.147	-1.608
10	8	402.085	406.155	-4.070
10	9	402.081	400.028	2.053
10	10	405.771	401.266	4.505
30	6	404.601	405.812	-1.211
30	7	400.922	400.903	0.019
30	8	404.604	404.585	0.019
30	9	404.605	405.813	-1.208
30	10	410.735	405.813	4.922
50	16	402.147	399.676	2.471
50	17	405.828	405.813	0.015
50	18	407.059	402.130	4.929
50	19	405.835	405.812	0.023
50	20	405.830	407.040	-1.210
100	B043	405.832	403.358	2.474
100	B044	400.918	407.040	-6.122
100	B045	403.371	399.676	3.695
100	B046	400.913	405.813	-4.900
100	B047	407.051	400.903	6.148
100	B048	405.829	403.358	2.471
100	B049	399.695	407.040	-7.345
100	B050	405.827	400.903	4.924
100	B051	402.152	407.040	-4.888
100	B052	403.377	405.812	-2.435
100	B053	403.378	398.448	4.930
100	B054	404.606	407.040	-2.434
100	B055	405.829	402.130	3.699
100	B056	400.921	403.358	-2.437
100	B057	404.600	403.358	1.242
100	B058	404.608	403.358	1.250
100	B059	407.054	404.585	2.469
100	B060	403.376	402.130	1.246
100	B061	410.742	403.358	7.384
100	B062	408.290	401.911	6.379
100	B063	403.377	407.040	-3.663
100	B064	405.830	403.358	2.472
	Max	410.742	407.040	7.384
	Average	404.495	403.599	0.896
	Min	399.695	395.154	-7.345
	Std Dev	2.565	2.880	3.836

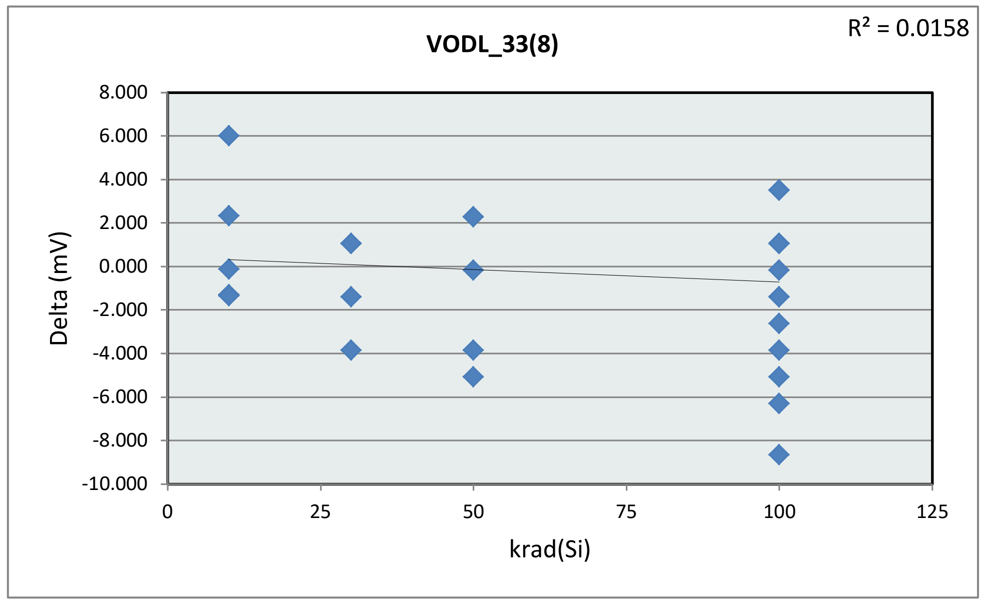


	VODH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	395.154	400.903	399.676	398.448
Average	401.750	404.585	404.094	403.683
Max	406.155	405.813	407.040	407.040
UL	430.000	430.000	430.000	430.000

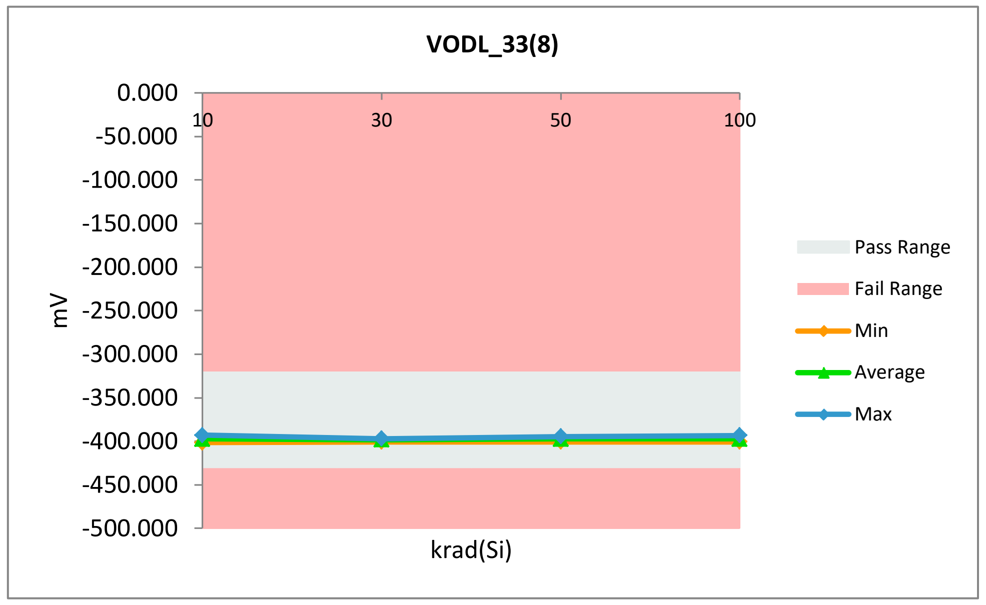


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-393.242	-393.125	-0.117
10	7	-399.382	-401.708	2.326
10	8	-394.472	-400.479	6.007
10	9	-394.476	-393.161	-1.315
10	10	-399.378	-398.034	-1.344
30	6	-399.507	-400.559	1.052
30	7	-395.820	-396.877	1.057
30	8	-398.276	-396.877	-1.399
30	9	-397.047	-398.104	1.057
30	10	-403.194	-399.331	-3.863
50	16	-395.823	-395.649	-0.174
50	17	-399.507	-394.422	-5.085
50	18	-400.732	-396.877	-3.855
50	19	-397.046	-399.332	2.286
50	20	-398.278	-400.559	2.281
100	B043	-398.276	-396.877	-1.399
100	B044	-397.052	-398.104	1.052
100	B045	-400.737	-394.422	-6.315
100	B046	-397.057	-398.104	1.047
100	B047	-401.967	-396.877	-5.090
100	B048	-398.279	-399.332	1.053
100	B049	-394.592	-398.104	3.512
100	B050	-399.510	-398.105	-1.405
100	B051	-397.046	-400.559	3.513
100	B052	-394.592	-398.104	3.512
100	B053	-397.048	-393.195	-3.853
100	B054	-395.819	-399.332	3.513
100	B055	-399.506	-396.877	-2.629
100	B056	-395.821	-395.649	-0.172
100	B057	-395.825	-396.877	1.052
100	B058	-395.817	-396.877	1.060
100	B059	-399.509	-400.559	1.050
100	B060	-397.049	-395.650	-1.399
100	B061	-401.960	-395.650	-6.310
100	B062	-401.957	-393.289	-8.668
100	B063	-395.821	-399.332	3.511
100	B064	-397.051	-396.877	-0.174
	Max	-393.242	-393.125	6.007
	Average	-397.797	-397.401	-0.395
	Min	-403.194	-401.708	-8.668
	Std Dev	2.439	2.317	3.281



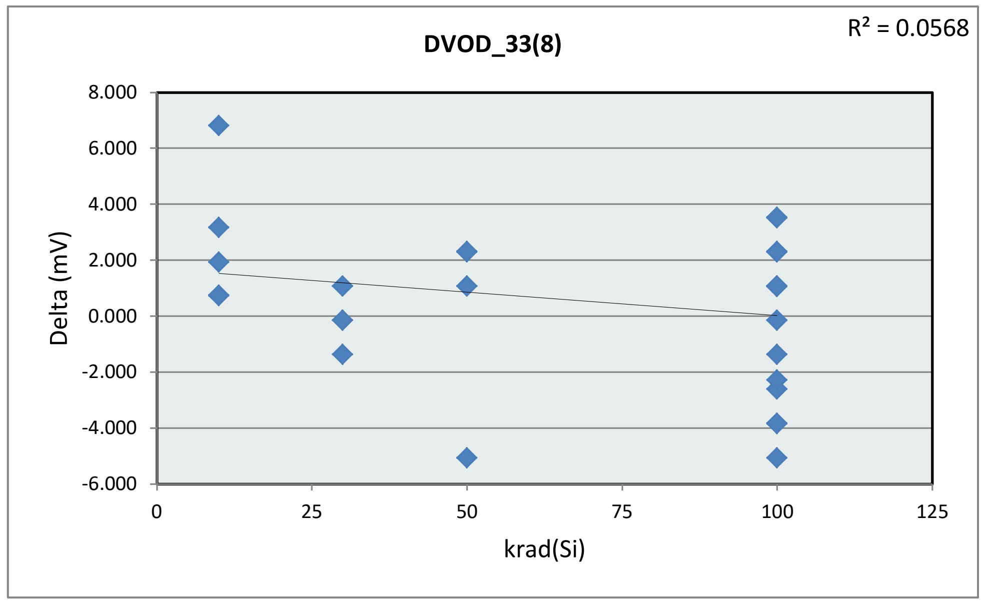
	VODL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-401.708	-400.559	-400.559	-400.559
Average	-397.301	-398.350	-397.368	-397.216
Max	-393.125	-396.877	-394.422	-393.195
UL	-320.000	-320.000	-320.000	-320.000



HDR UnBiased TID Report
SN55LVCP22A-SP

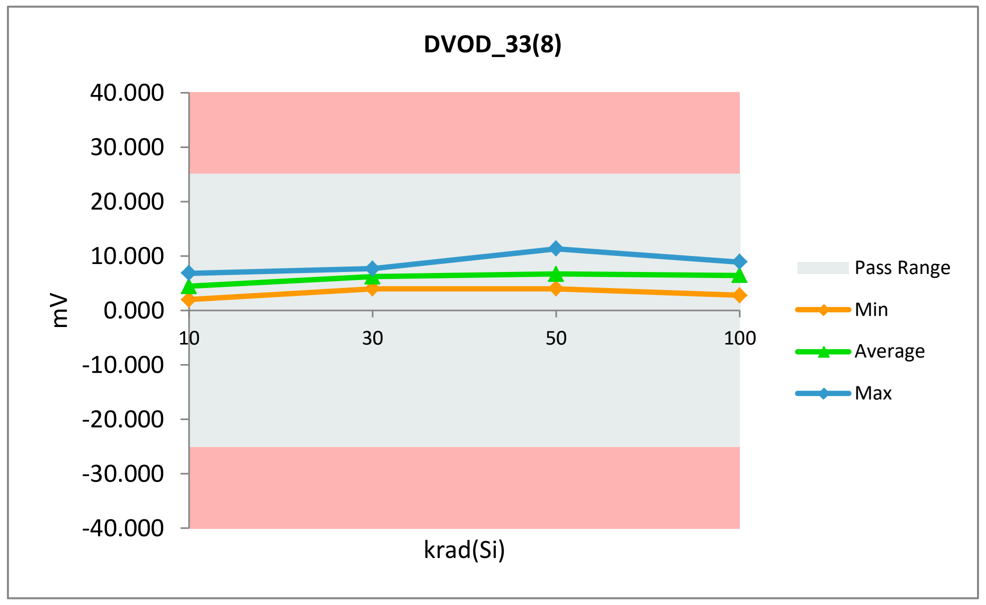
	DVOD_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	8.846	2.029	6.817
10	7	5.158	4.440	0.718
10	8	7.612	5.676	1.936
10	9	7.605	6.867	0.738
10	10	6.393	3.231	3.162
30	6	5.093	5.253	-0.160
30	7	5.102	4.026	1.076
30	8	6.328	7.708	-1.380
30	9	7.558	7.708	-0.150
30	10	7.542	6.481	1.061
50	16	6.324	4.026	2.298
50	17	6.321	11.391	-5.070
50	18	6.326	5.253	1.074
50	19	8.789	6.481	2.308
50	20	7.551	6.481	1.070
100	B043	7.556	6.481	1.075
100	B044	3.865	8.935	-5.070
100	B045	2.634	5.253	-2.619
100	B046	3.857	7.708	-3.851
100	B047	5.084	4.026	1.058
100	B048	7.551	4.026	3.525
100	B049	5.102	8.936	-3.834
100	B050	6.317	2.798	3.519
100	B051	5.106	6.480	-1.374
100	B052	8.785	7.708	1.077
100	B053	6.330	5.254	1.076
100	B054	8.787	7.708	1.079
100	B055	6.323	5.254	1.069
100	B056	5.099	7.708	-2.609
100	B057	8.775	6.481	2.294
100	B058	8.791	6.481	2.310
100	B059	7.545	4.026	3.519
100	B060	6.327	6.481	-0.154
100	B061	8.782	7.708	1.074
100	B062	6.333	8.622	-2.289
100	B063	7.556	7.708	-0.152
100	B064	8.779	6.481	2.298
	Max	8.846	11.391	6.817
	Average	6.698	6.198	0.501
	Min	2.634	2.029	-5.070
	Std Dev	1.612	1.946	2.539



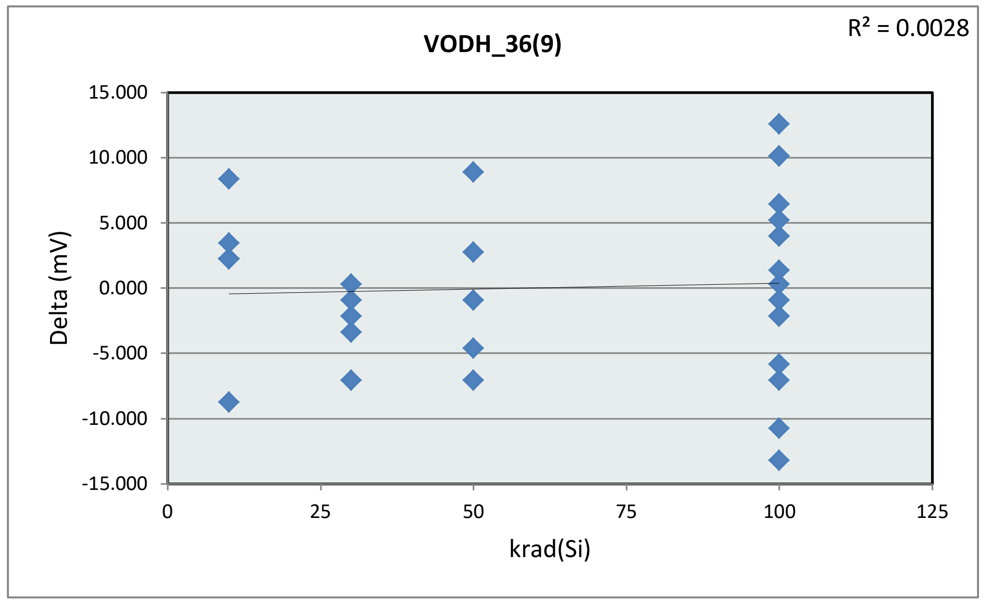
	DVOD_33(8)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.029	4.026	4.026	2.798
Average	4.449	6.235	6.726	6.467
Max	6.867	7.708	11.391	8.936
UL	25.000	25.000	25.000	25.000

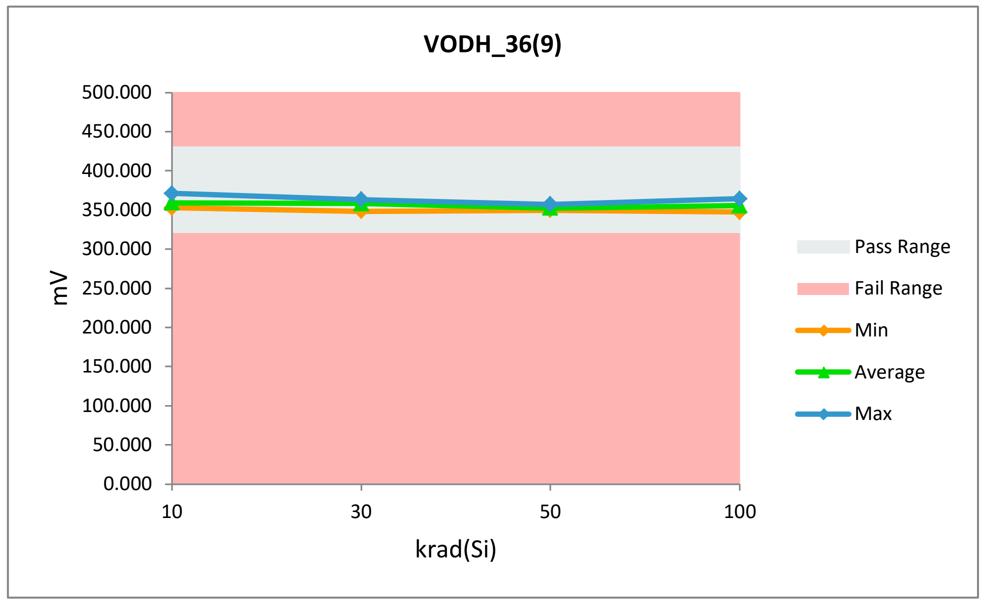


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	358.575	356.343	2.232
10	7	362.255	370.999	-8.744
10	8	364.709	362.450	2.259
10	9	362.254	353.898	8.356
10	10	356.121	352.678	3.443
30	6	359.768	363.152	-3.384
30	7	346.270	348.430	-2.160
30	8	356.087	363.154	-7.067
30	9	357.313	357.018	0.295
30	10	358.541	359.470	-0.929
50	16	349.952	354.562	-4.610
50	17	349.952	357.019	-7.067
50	18	349.952	350.884	-0.932
50	19	352.407	349.657	2.750
50	20	358.540	349.657	8.883
100	B043	352.406	358.242	-5.836
100	B044	354.860	357.018	-2.158
100	B045	364.677	354.566	10.111
100	B046	351.179	353.338	-2.159
100	B047	359.771	353.336	6.435
100	B048	351.180	364.378	-13.198
100	B049	349.952	352.113	-2.161
100	B050	351.179	352.111	-0.932
100	B051	357.314	358.248	-0.934
100	B052	360.996	350.885	10.111
100	B053	360.999	348.429	12.570
100	B054	347.498	349.656	-2.158
100	B055	357.316	357.018	0.298
100	B056	353.632	360.698	-7.066
100	B057	364.675	360.701	3.974
100	B058	353.635	347.203	6.432
100	B059	360.998	357.020	3.978
100	B060	357.312	353.335	3.977
100	B061	352.406	363.149	-10.743
100	B062	354.861	353.525	1.336
100	B063	354.861	360.700	-5.839
100	B064	363.452	358.242	5.210
	Max	364.709	370.999	12.570
	Average	356.158	356.035	0.124
	Min	346.270	347.203	-13.198
	Std Dev	5.071	5.352	6.108



	VODH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	352.678	348.430	349.657	347.203
Average	359.274	358.245	352.356	355.632
Max	370.999	363.154	357.019	364.378
UL	430.000	430.000	430.000	430.000



HDR UnBiased TID Report
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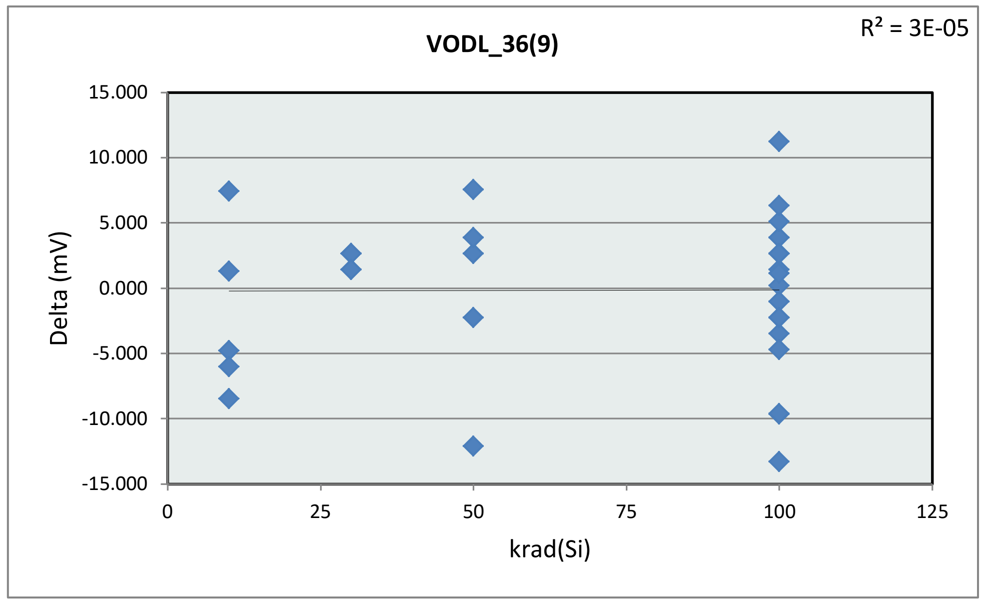
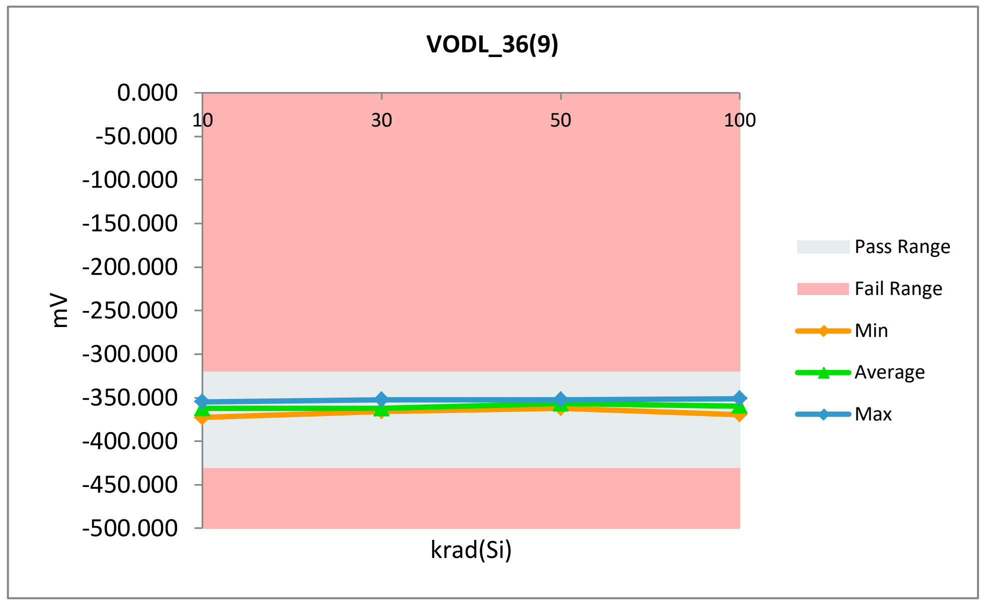
	VODL_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-364.259	-359.464	-4.795
10	7	-365.488	-372.903	7.415
10	8	-366.716	-368.016	1.300
10	9	-363.035	-357.022	-6.013
10	10	-363.032	-354.578	-8.454
30	6	-363.124	-365.764	2.640
30	7	-349.620	-352.262	2.642
30	8	-364.349	-365.761	1.412
30	9	-361.897	-364.534	2.637
30	10	-361.896	-363.310	1.414
50	16	-354.530	-357.174	2.644
50	17	-354.530	-362.080	7.550
50	18	-352.075	-355.943	3.868
50	19	-359.438	-357.170	-2.268
50	20	-364.351	-352.262	-12.089
100	B043	-359.439	-362.083	2.644
100	B044	-359.441	-358.399	-1.042
100	B045	-369.261	-359.624	-9.637
100	B046	-354.530	-358.398	3.868
100	B047	-360.665	-357.172	-3.493
100	B048	-358.211	-369.446	11.235
100	B049	-352.076	-354.714	2.638
100	B050	-354.530	-355.943	1.413
100	B051	-358.213	-362.078	3.865
100	B052	-360.668	-358.397	-2.271
100	B053	-365.575	-352.263	-13.312
100	B054	-350.847	-353.489	2.642
100	B055	-359.439	-359.626	0.187
100	B056	-356.987	-362.081	5.094
100	B057	-366.808	-364.533	-2.275
100	B058	-360.666	-351.034	-9.632
100	B059	-360.667	-359.625	-1.042
100	B060	-361.897	-357.174	-4.723
100	B061	-360.667	-366.993	6.326
100	B062	-359.439	-360.587	1.148
100	B063	-359.439	-362.080	2.641
100	B064	-365.576	-363.310	-2.266
	Max	-349.620	-351.034	11.235
	Average	-360.091	-359.927	-0.165
	Min	-369.261	-372.903	-13.312
	Std Dev	4.774	5.169	5.552



	VODL_36(9)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-372.903	-365.764	-362.080	-369.446
Average	-362.397	-362.326	-356.926	-359.502
Max	-354.578	-352.262	-352.262	-351.034
UL	-320.000	-320.000	-320.000	-320.000



HDR UnBiased TID Report
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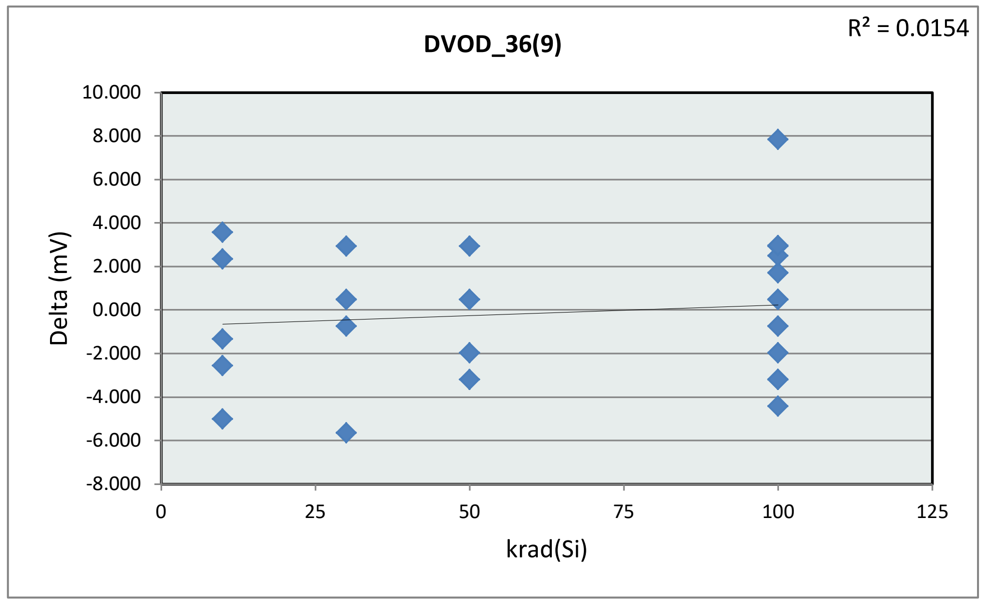
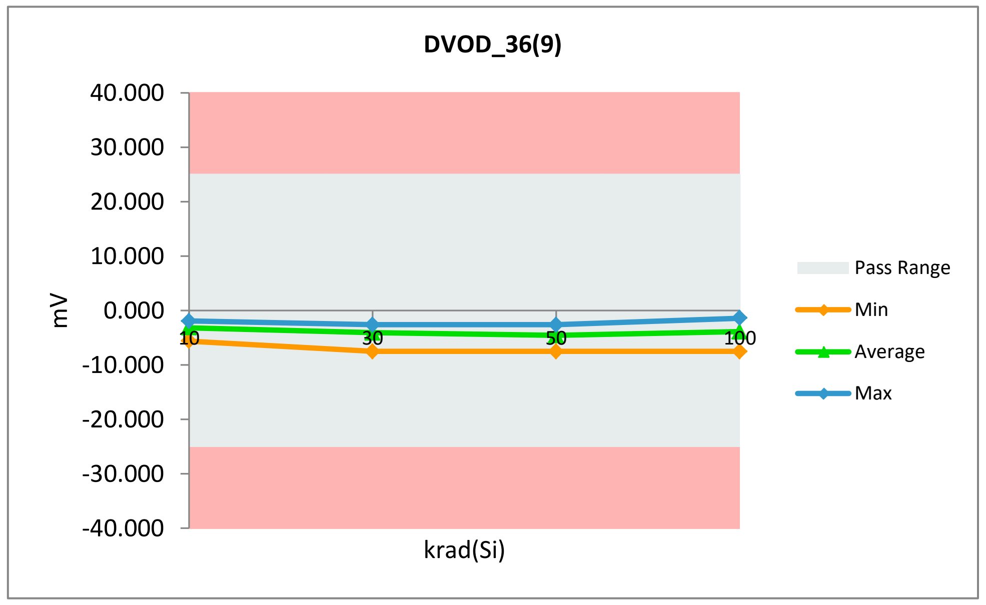
		DVOD_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-5.684	-3.121	-2.563
10	7	-3.232	-1.904	-1.328
10	8	-2.006	-5.566	3.560
10	9	-0.780	-3.124	2.344
10	10	-6.912	-1.901	-5.011
30	6	-3.356	-2.611	-0.745
30	7	-3.350	-3.832	0.482
30	8	-8.262	-2.607	-5.655
30	9	-4.584	-7.517	2.933
30	10	-3.355	-3.840	0.485
50	16	-4.579	-2.611	-1.968
50	17	-4.577	-5.061	0.484
50	18	-2.123	-5.060	2.937
50	19	-7.031	-7.513	0.482
50	20	-5.811	-2.605	-3.206
100	B043	-7.033	-3.841	-3.192
100	B044	-4.581	-1.380	-3.201
100	B045	-4.584	-5.059	0.475
100	B046	-3.351	-5.061	1.710
100	B047	-0.894	-3.836	2.942
100	B048	-7.031	-5.067	-1.964
100	B049	-2.124	-2.601	0.477
100	B050	-3.352	-3.832	0.480
100	B051	-0.899	-3.830	2.931
100	B052	0.328	-7.512	7.840
100	B053	-4.577	-3.834	-0.743
100	B054	-3.349	-3.833	0.484
100	B055	-2.123	-2.609	0.486
100	B056	-3.355	-1.383	-1.972
100	B057	-2.133	-3.831	1.698
100	B058	-7.031	-3.830	-3.201
100	B059	0.331	-2.605	2.936
100	B060	-4.585	-3.839	-0.746
100	B061	-8.262	-3.844	-4.418
100	B062	-4.578	-7.062	2.484
100	B063	-4.578	-1.379	-3.199
100	B064	-2.124	-5.068	2.944
	Max	0.331	-1.379	7.840
	Average	-3.933	-3.892	-0.041
	Min	-8.262	-7.517	-5.655
	Std Dev	2.253	1.667	2.862



	DVOD_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-5.566	-7.517	-7.513	-7.512
Average	-3.123	-4.081	-4.570	-3.870
Max	-1.901	-2.607	-2.605	-1.379
UL	25.000	25.000	25.000	25.000



HDR UnBiased TID Report
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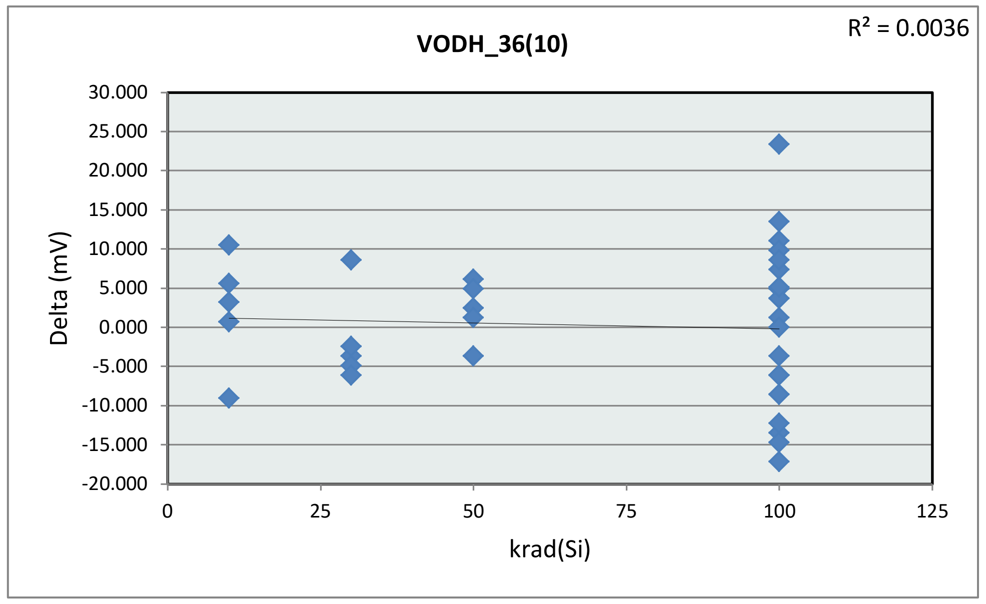
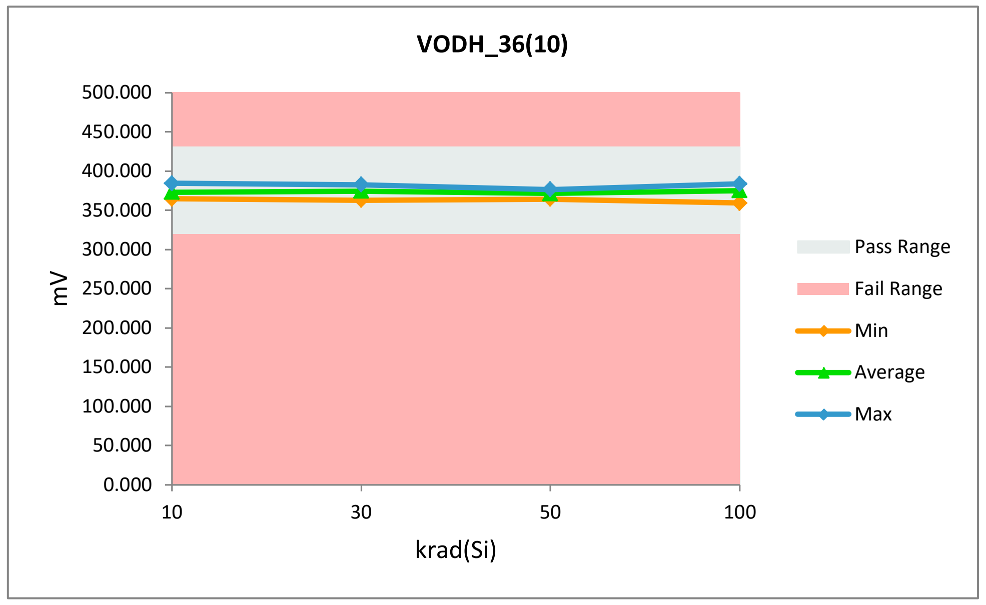
	VODH_36(10)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	375.079	364.578	10.501
10	7	375.075	384.125	-9.050
10	8	379.985	376.798	3.187
10	9	370.162	369.448	0.714
10	10	375.079	369.461	5.618
30	6	372.676	376.356	-3.680
30	7	360.403	362.855	-2.452
30	8	377.591	382.493	-4.902
30	9	371.453	377.583	-6.130
30	10	381.266	372.674	8.592
50	16	366.539	364.082	2.457
50	17	372.676	376.356	-3.680
50	18	373.907	367.764	6.143
50	19	376.366	375.128	1.238
50	20	378.816	373.901	4.915
100	B043	376.363	380.038	-3.675
100	B044	367.766	381.265	-13.499
100	B045	383.724	372.674	11.050
100	B046	370.216	376.356	-6.140
100	B047	381.265	367.764	13.501
100	B048	375.133	383.720	-8.587
100	B049	359.176	376.356	-17.180
100	B050	377.585	370.219	7.366
100	B051	367.772	382.492	-14.720
100	B052	370.225	376.356	-6.131
100	B053	382.503	359.173	23.330
100	B054	368.998	377.583	-8.585
100	B055	372.677	368.992	3.685
100	B056	371.452	370.219	1.233
100	B057	382.497	382.493	0.004
100	B058	373.912	368.992	4.920
100	B059	383.724	373.901	9.823
100	B060	373.907	370.219	3.688
100	B061	376.362	382.492	-6.130
100	B062	377.593	372.454	5.139
100	B063	371.452	383.720	-12.268
100	B064	383.727	375.128	8.599
	Max	383.727	384.125	23.330
	Average	374.462	374.222	0.240
	Min	359.176	359.173	-17.180
	Std Dev	5.954	6.413	8.726



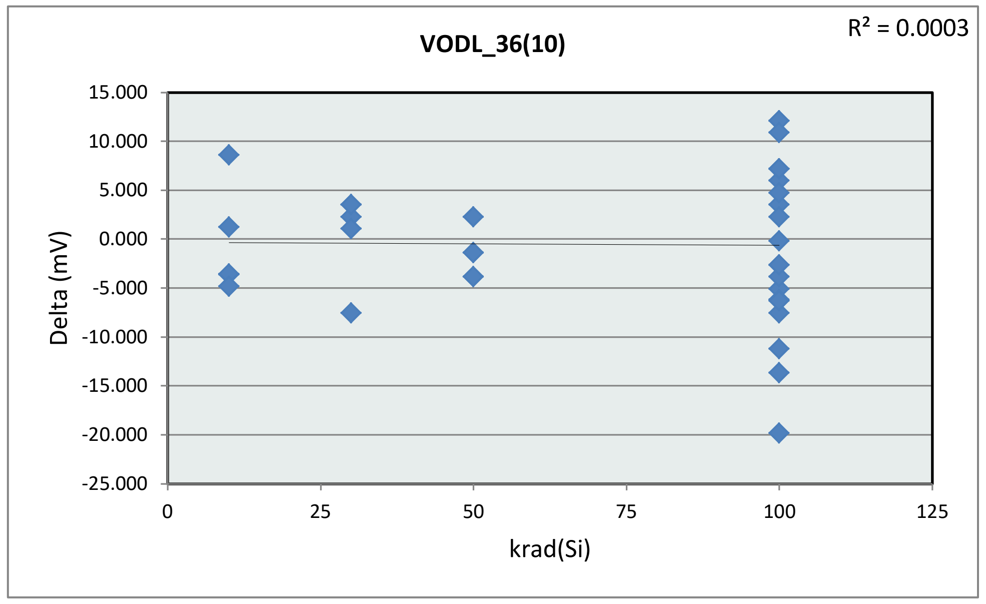
	VODH_36(10)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	430	mV
Min Limit	320	mV

krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	364.578	362.855	364.082	359.173
Average	372.882	374.392	371.446	375.118
Max	384.125	382.493	376.356	383.720
UL	430.000	430.000	430.000	430.000

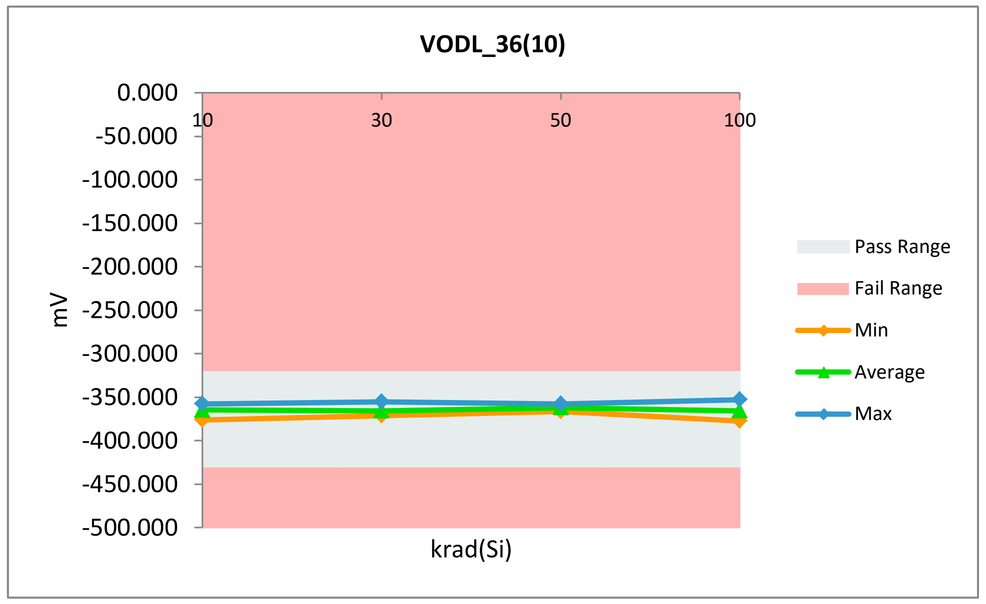


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-362.565	-358.929	-3.636
10	7	-367.478	-376.065	8.587
10	8	-367.477	-368.727	1.250
10	9	-361.345	-357.745	-3.600
10	10	-366.247	-361.397	-4.850
30	6	-366.367	-368.648	2.281
30	7	-354.087	-355.147	1.060
30	8	-367.590	-371.103	3.513
30	9	-363.907	-367.420	3.513
30	10	-372.509	-364.966	-7.543
50	16	-358.999	-357.602	-1.397
50	17	-363.912	-362.511	-1.401
50	18	-363.909	-360.057	-3.852
50	19	-363.905	-366.193	2.288
50	20	-367.592	-363.739	-3.853
100	B043	-366.362	-372.330	5.968
100	B044	-365.139	-368.648	3.509
100	B045	-378.644	-364.966	-13.678
100	B046	-363.916	-366.193	2.277
100	B047	-373.737	-362.511	-11.226
100	B048	-365.138	-377.240	12.102
100	B049	-352.859	-360.056	7.197
100	B050	-367.596	-362.512	-5.084
100	B051	-360.222	-372.330	12.108
100	B052	-360.224	-364.966	4.742
100	B053	-372.499	-352.692	-19.807
100	B054	-360.223	-367.421	7.198
100	B055	-367.593	-360.056	-7.537
100	B056	-362.681	-360.056	-2.625
100	B057	-371.277	-371.102	-0.175
100	B058	-362.676	-358.829	-3.847
100	B059	-373.734	-367.421	-6.313
100	B060	-363.908	-361.284	-2.624
100	B061	-363.909	-371.103	7.194
100	B062	-367.588	-361.388	-6.200
100	B063	-362.680	-373.558	10.878
100	B064	-370.048	-363.738	-6.310
	Max	-352.859	-352.692	12.108
	Average	-365.420	-364.882	-0.538
	Min	-378.644	-377.240	-19.807
	Std Dev	5.206	5.810	7.107



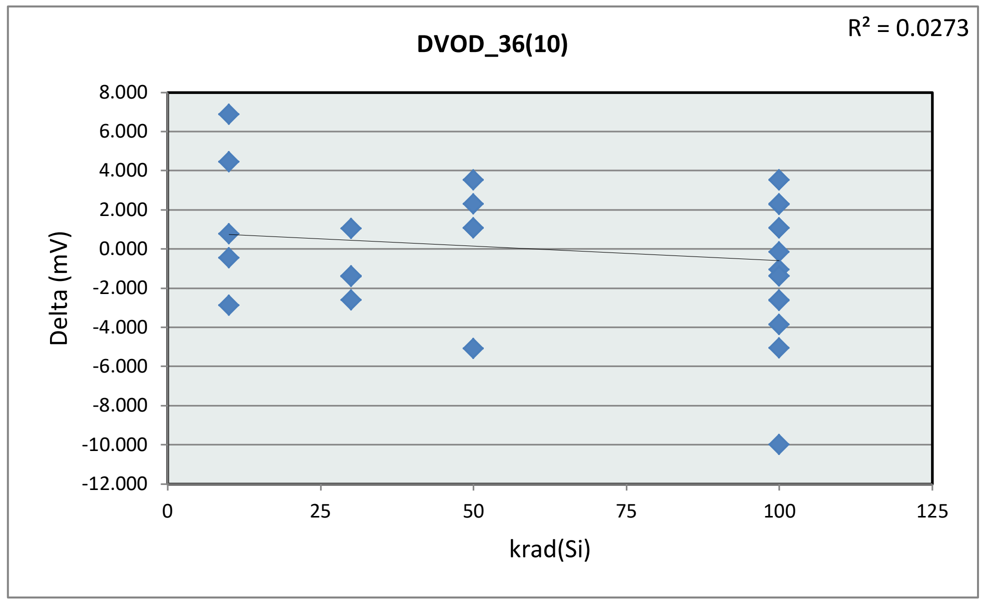
	VODL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-376.065	-371.103	-366.193	-377.240
Average	-364.573	-365.457	-362.020	-365.473
Max	-357.745	-355.147	-357.602	-352.692
UL	-320.000	-320.000	-320.000	-320.000



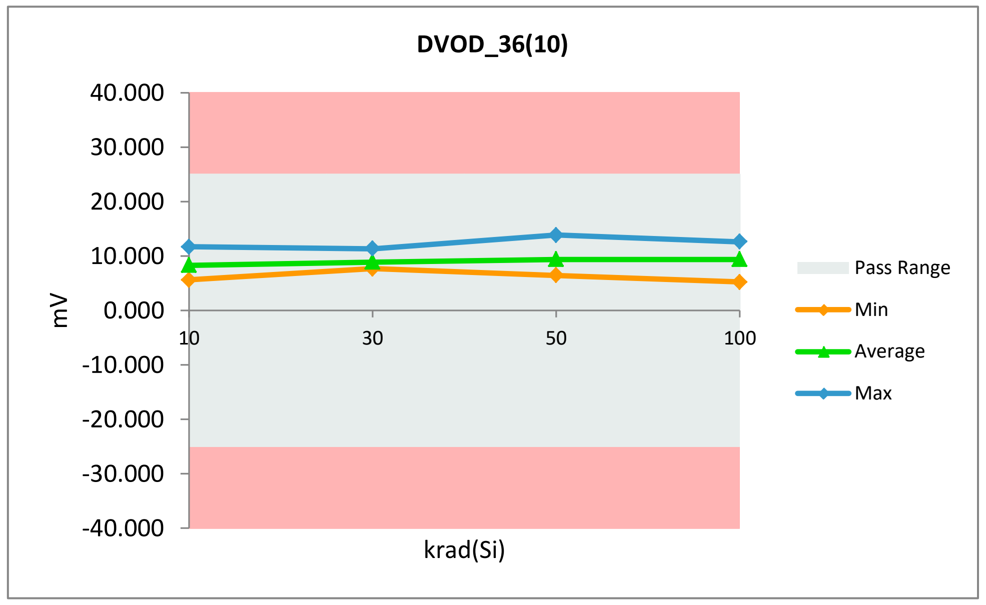
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVOD_36(10)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	12.513	5.649	6.864
10	7	7.597	8.060	-0.463
10	8	12.508	8.071	4.437
10	9	8.817	11.703	-2.886
10	10	8.832	8.064	0.768
30	6	6.310	7.708	-1.398
30	7	6.316	7.708	-1.392
30	8	10.000	11.390	-1.390
30	9	7.546	10.163	-2.617
30	10	8.757	7.708	1.049
50	16	7.540	6.481	1.059
50	17	8.764	13.845	-5.081
50	18	9.998	7.708	2.290
50	19	12.461	8.935	3.526
50	20	11.224	10.162	1.062
100	B043	10.001	7.708	2.293
100	B044	2.626	12.617	-9.991
100	B045	5.080	7.708	-2.628
100	B046	6.300	10.162	-3.862
100	B047	7.527	5.253	2.274
100	B048	9.995	6.480	3.515
100	B049	6.317	11.390	-5.073
100	B050	9.989	7.707	2.282
100	B051	7.550	10.162	-2.612
100	B052	10.002	11.390	-1.388
100	B053	10.004	6.481	3.523
100	B054	8.775	10.162	-1.387
100	B055	5.084	8.935	-3.851
100	B056	8.771	10.163	-1.392
100	B057	11.220	11.390	-0.170
100	B058	11.236	10.162	1.074
100	B059	9.990	6.480	3.510
100	B060	9.998	8.935	1.063
100	B061	12.453	11.389	1.064
100	B062	10.005	11.066	-1.061
100	B063	8.773	10.162	-1.389
100	B064	13.680	11.390	2.290
	Max	13.680	13.845	6.864
	Average	9.042	9.207	-0.165
	Min	2.626	5.253	-9.991
	Std Dev	2.394	2.086	3.222

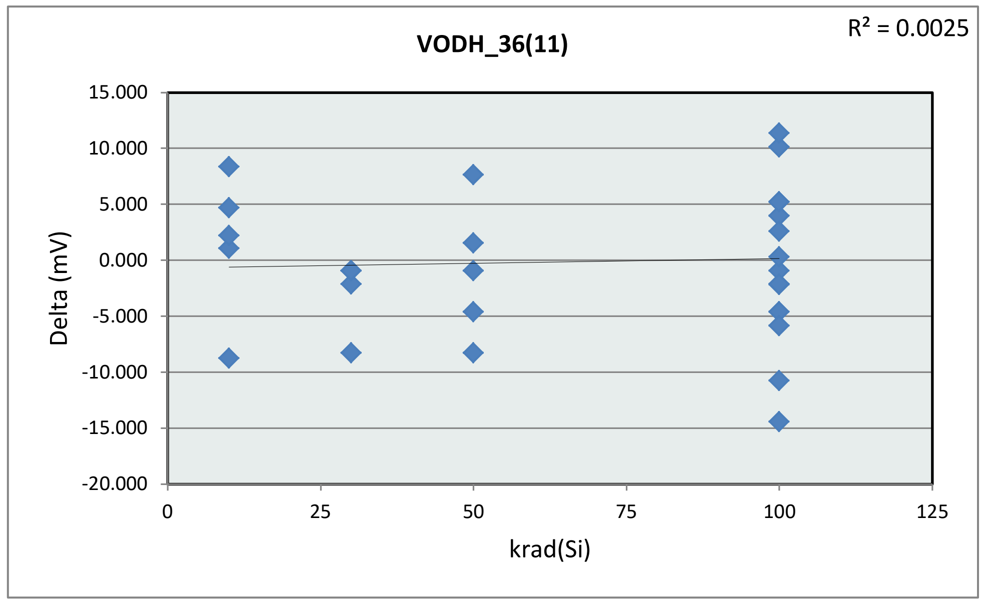


	DVOD_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	5.649	7.708	6.481	5.253
Average	8.309	8.935	9.426	9.422
Max	11.703	11.390	13.845	12.617
UL	25.000	25.000	25.000	25.000

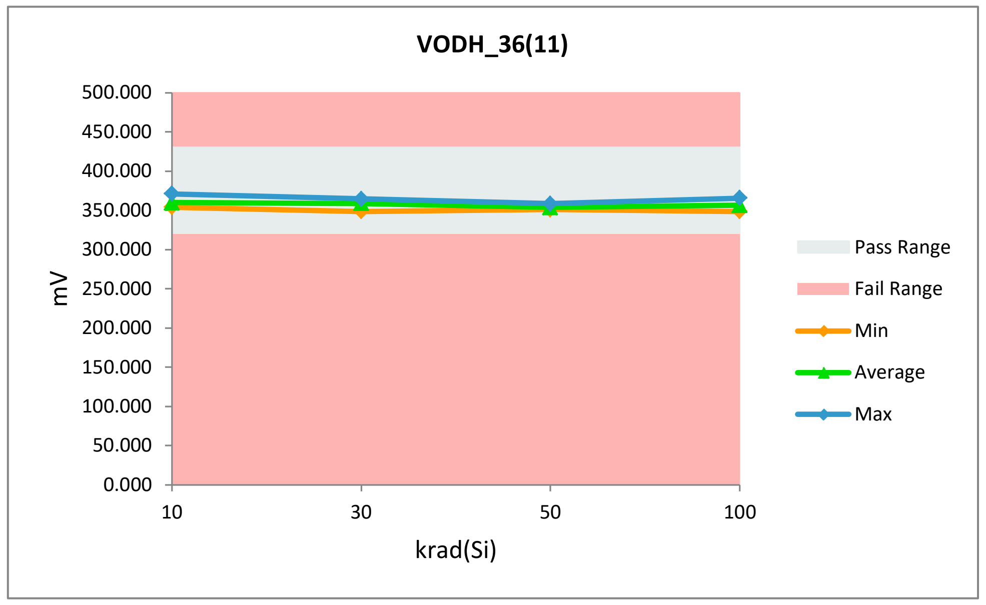


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	361.029	356.341	4.688
10	7	362.255	370.997	-8.742
10	8	364.709	363.669	1.040
10	9	362.254	353.896	8.358
10	10	356.120	353.897	2.223
30	6	360.994	363.151	-2.157
30	7	347.496	348.428	-0.932
30	8	356.086	364.380	-8.294
30	9	357.311	358.244	-0.933
30	10	358.540	359.468	-0.928
50	16	351.178	355.788	-4.610
50	17	349.951	358.244	-8.293
50	18	351.178	352.109	-0.931
50	19	352.406	350.883	1.523
50	20	358.539	350.882	7.657
100	B043	353.633	358.241	-4.608
100	B044	356.086	358.244	-2.158
100	B045	364.675	354.564	10.111
100	B046	352.406	354.563	-2.157
100	B047	359.770	354.562	5.208
100	B048	351.179	365.604	-14.425
100	B049	348.723	353.339	-4.616
100	B050	351.178	352.109	-0.931
100	B051	357.313	359.473	-2.160
100	B052	360.995	350.883	10.112
100	B053	360.997	349.655	11.342
100	B054	347.497	349.655	-2.158
100	B055	357.315	357.016	0.299
100	B056	353.631	359.470	-5.839
100	B057	364.674	359.473	5.201
100	B058	353.633	348.429	5.204
100	B059	362.224	358.245	3.979
100	B060	358.538	354.561	3.977
100	B061	353.632	364.375	-10.743
100	B062	356.087	353.524	2.563
100	B063	356.087	361.926	-5.839
100	B064	364.678	359.468	5.210
	Max	364.709	370.997	11.342
	Average	356.622	356.696	-0.075
	Min	347.496	348.428	-14.425
	Std Dev	5.052	5.285	6.091

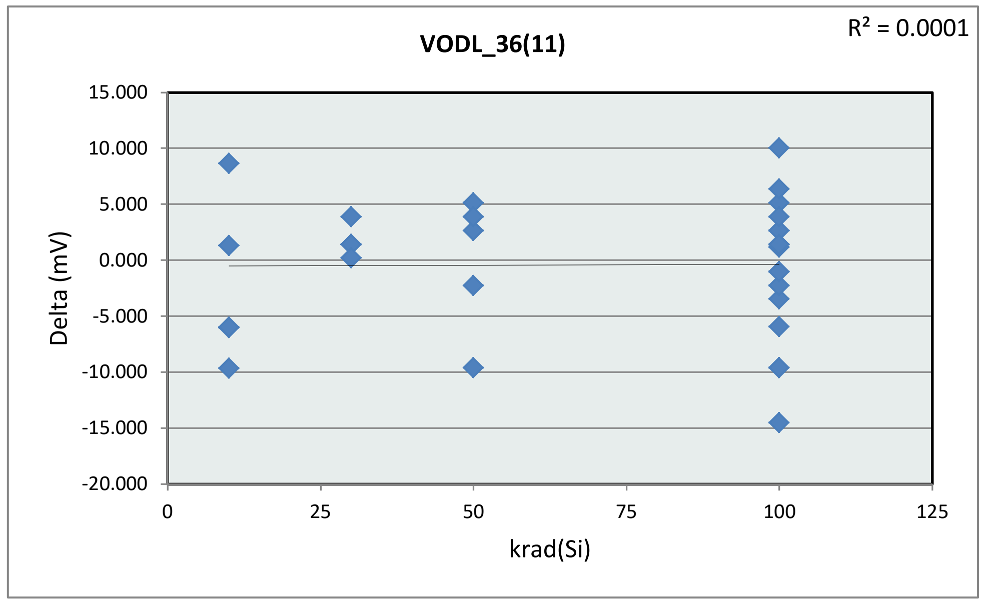


	VODH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	353.896	348.428	350.882	348.429
Average	359.760	358.734	353.581	356.245
Max	370.997	364.380	358.244	365.604
UL	430.000	430.000	430.000	430.000

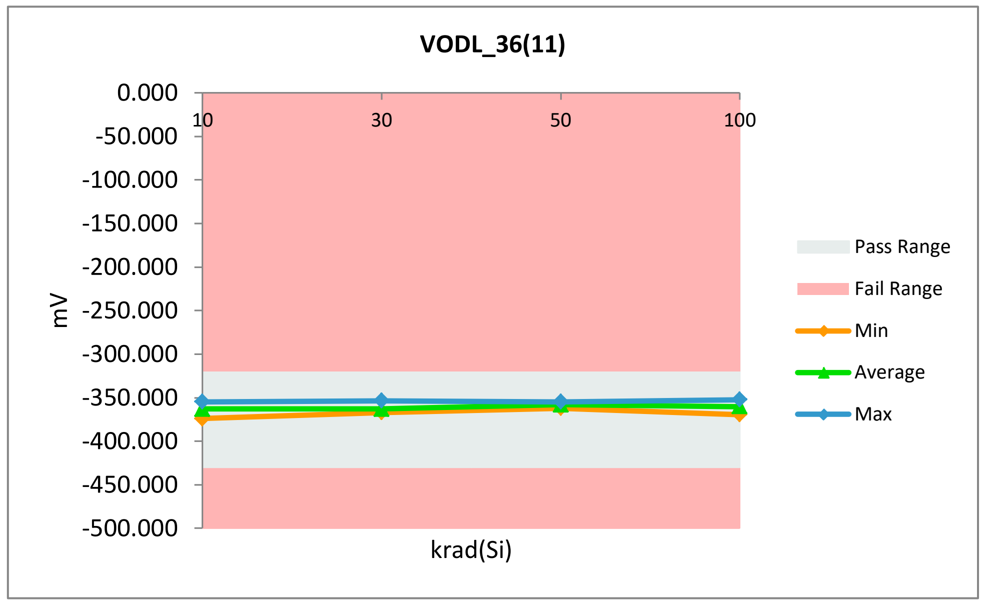


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-365.487	-359.466	-6.021
10	7	-365.488	-374.127	8.639
10	8	-366.716	-368.018	1.302
10	9	-364.262	-358.246	-6.016
10	10	-364.260	-354.581	-9.679
30	6	-364.352	-365.765	1.413
30	7	-352.076	-353.490	1.414
30	8	-365.578	-366.989	1.411
30	9	-361.898	-365.763	3.865
30	10	-363.125	-363.312	0.187
50	16	-355.759	-358.402	2.643
50	17	-356.985	-362.082	5.097
50	18	-353.304	-357.172	3.868
50	19	-360.667	-358.399	-2.268
50	20	-364.352	-354.718	-9.634
100	B043	-358.213	-363.312	5.099
100	B044	-359.442	-360.854	1.412
100	B045	-369.262	-359.626	-9.636
100	B046	-356.986	-359.627	2.641
100	B047	-361.894	-358.401	-3.493
100	B048	-359.439	-369.447	10.008
100	B049	-353.304	-354.716	1.412
100	B050	-354.532	-355.945	1.413
100	B051	-359.442	-362.079	2.637
100	B052	-361.896	-359.626	-2.270
100	B053	-366.804	-352.264	-14.540
100	B054	-352.075	-354.718	2.643
100	B055	-360.667	-359.628	-1.039
100	B056	-358.215	-362.082	3.867
100	B057	-368.036	-365.761	-2.275
100	B058	-361.894	-352.262	-9.632
100	B059	-361.895	-360.853	-1.042
100	B060	-363.126	-357.175	-5.951
100	B061	-360.669	-366.995	6.326
100	B062	-360.667	-361.815	1.148
100	B063	-360.668	-362.081	1.413
100	B064	-365.578	-364.539	-1.039
	Max	-352.075	-352.262	10.008
	Average	-361.054	-360.658	-0.397
	Min	-369.262	-374.127	-14.540
	Std Dev	4.490	5.051	5.460

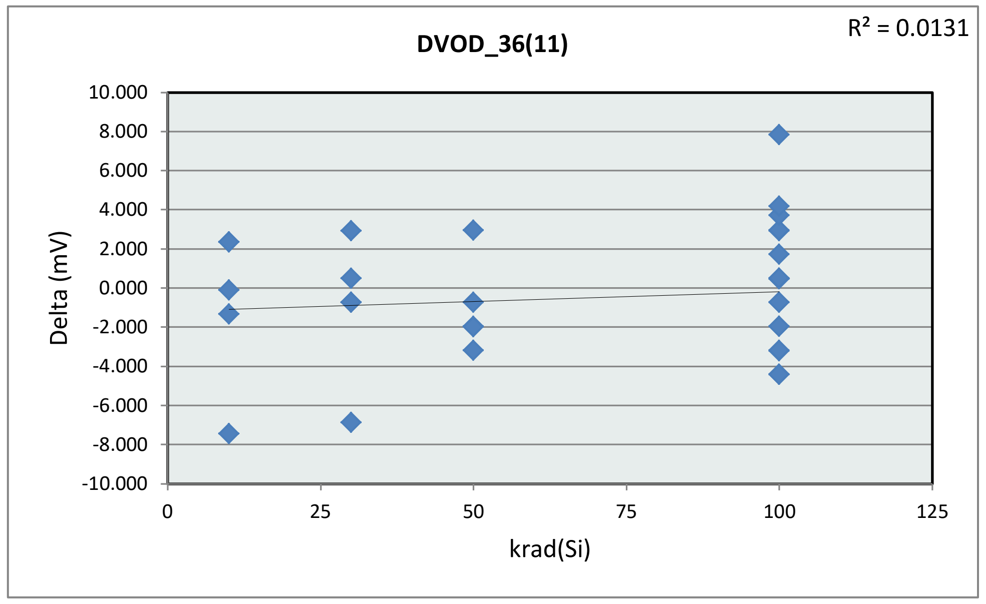


	VODL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-374.127	-366.989	-362.082	-369.447
Average	-362.888	-363.064	-358.155	-360.173
Max	-354.581	-353.490	-354.718	-352.262
UL	-320.000	-320.000	-320.000	-320.000

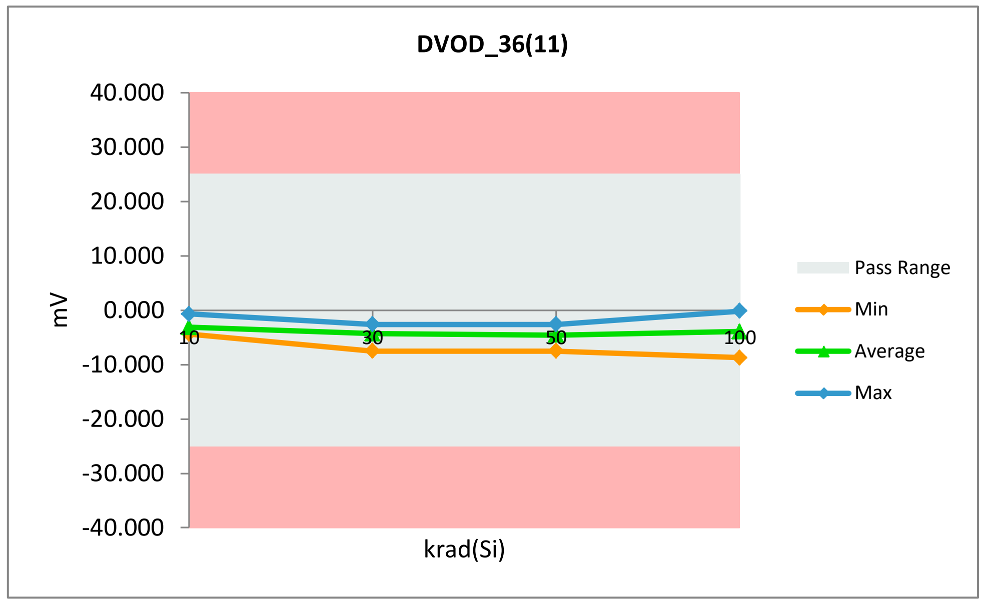


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-4.458	-3.125	-1.333
10	7	-3.233	-3.130	-0.103
10	8	-2.007	-4.349	2.342
10	9	-2.008	-4.350	2.342
10	10	-8.140	-0.685	-7.455
30	6	-3.358	-2.614	-0.744
30	7	-4.580	-5.062	0.482
30	8	-9.492	-2.609	-6.883
30	9	-4.587	-7.520	2.933
30	10	-4.585	-3.843	-0.742
50	16	-4.581	-2.614	-1.967
50	17	-7.034	-3.838	-3.196
50	18	-2.126	-5.063	2.937
50	19	-8.261	-7.516	-0.745
50	20	-5.813	-3.836	-1.977
100	B043	-4.581	-5.071	0.490
100	B044	-3.356	-2.611	-0.745
100	B045	-4.587	-5.062	0.475
100	B046	-4.580	-5.064	0.484
100	B047	-2.124	-3.839	1.715
100	B048	-8.260	-3.843	-4.417
100	B049	-4.581	-1.377	-3.204
100	B050	-3.354	-3.835	0.481
100	B051	-2.128	-2.606	0.478
100	B052	-0.901	-8.743	7.842
100	B053	-5.807	-2.610	-3.197
100	B054	-4.578	-5.064	0.486
100	B055	-3.353	-2.611	-0.742
100	B056	-4.585	-2.612	-1.973
100	B057	-3.362	-6.288	2.926
100	B058	-8.261	-3.833	-4.428
100	B059	0.329	-2.608	2.937
100	B060	-4.588	-2.615	-1.973
100	B061	-7.037	-2.621	-4.416
100	B062	-4.580	-8.291	3.711
100	B063	-4.581	-0.155	-4.425
100	B064	-0.900	-5.072	4.172
	Max	0.329	-0.155	7.842
	Average	-4.433	-3.962	-0.471
	Min	-9.492	-8.743	-7.455
	Std Dev	2.258	1.934	3.190

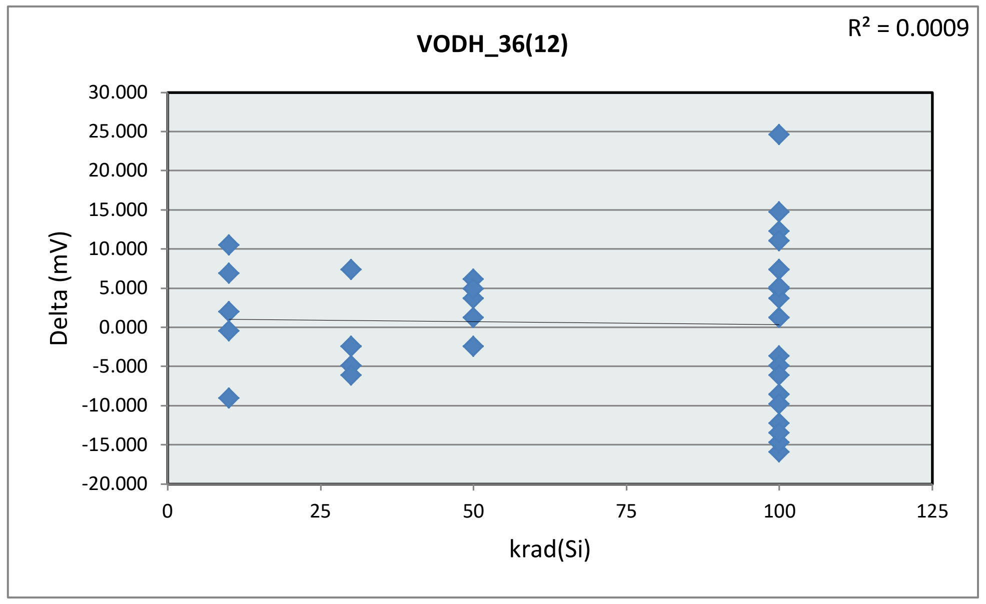


	DVOD_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-4.350	-7.520	-7.516	-8.743
Average	-3.128	-4.330	-4.573	-3.929
Max	-0.685	-2.609	-2.614	-0.155
UL	25.000	25.000	25.000	25.000

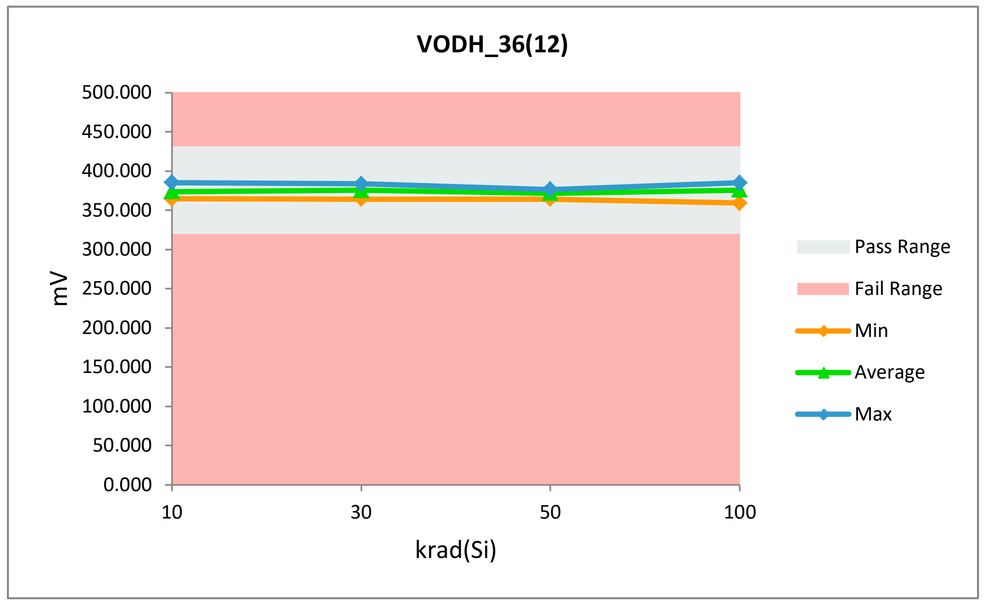


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	375.077	364.569	10.508
10	7	376.300	385.341	-9.041
10	8	379.983	378.014	1.969
10	9	370.160	370.662	-0.502
10	10	376.304	369.454	6.850
30	6	373.902	376.356	-2.454
30	7	361.629	364.082	-2.453
30	8	378.817	383.720	-4.903
30	9	372.679	378.810	-6.131
30	10	381.265	373.901	7.364
50	16	367.766	364.082	3.684
50	17	373.902	376.356	-2.454
50	18	373.905	367.764	6.141
50	19	376.364	375.128	1.236
50	20	380.042	375.128	4.914
100	B043	377.589	381.265	-3.676
100	B044	368.992	381.265	-12.273
100	B045	384.950	372.674	12.276
100	B046	368.987	377.583	-8.596
100	B047	382.491	367.764	14.727
100	B048	375.131	383.720	-8.589
100	B049	360.402	376.356	-15.954
100	B050	378.811	371.446	7.365
100	B051	368.998	383.720	-14.722
100	B052	371.452	376.356	-4.904
100	B053	383.729	359.173	24.556
100	B054	368.997	378.810	-9.813
100	B055	373.903	368.992	4.911
100	B056	372.678	371.446	1.232
100	B057	383.723	382.492	1.231
100	B058	376.365	368.991	7.374
100	B059	384.950	373.901	11.049
100	B060	375.133	371.446	3.687
100	B061	377.588	383.720	-6.132
100	B062	378.819	373.680	5.139
100	B063	371.451	384.947	-13.496
100	B064	386.181	375.128	11.053
	Max	386.181	385.341	24.556
	Average	375.390	374.817	0.572
	Min	360.402	359.173	-15.954
	Std Dev	6.083	6.598	9.061

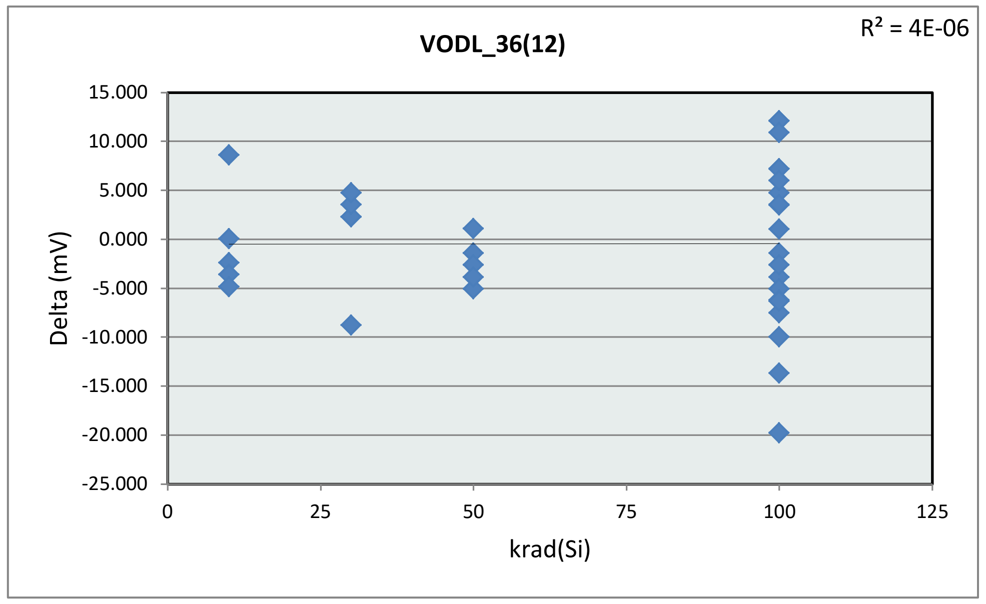


	VODH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	364.569	364.082	364.082	359.173
Average	373.608	375.374	371.692	375.676
Max	385.341	383.720	376.356	384.947
UL	430.000	430.000	430.000	430.000

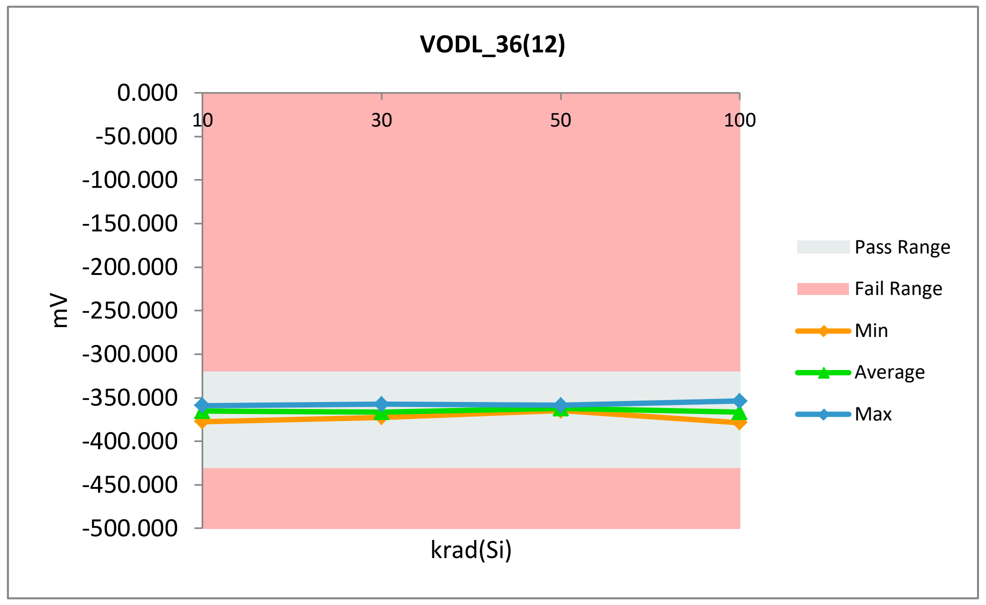


HDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-362.567	-360.159	-2.408
10	7	-368.707	-377.294	8.587
10	8	-368.706	-368.732	0.026
10	9	-362.575	-358.974	-3.601
10	10	-367.476	-362.626	-4.850
30	6	-367.596	-369.876	2.280
30	7	-355.316	-357.602	2.286
30	8	-368.819	-372.330	3.511
30	9	-363.908	-368.648	4.740
30	10	-373.738	-364.966	-8.772
50	16	-360.229	-358.829	-1.400
50	17	-365.141	-362.511	-2.630
50	18	-365.138	-360.057	-5.081
50	19	-363.906	-364.966	1.060
50	20	-368.821	-364.966	-3.855
100	B043	-366.364	-373.558	7.194
100	B044	-365.141	-369.875	4.734
100	B045	-379.873	-366.193	-13.680
100	B046	-363.917	-367.421	3.504
100	B047	-374.966	-364.966	-10.000
100	B048	-366.367	-378.467	12.100
100	B049	-354.088	-361.284	7.196
100	B050	-368.825	-364.966	-3.859
100	B051	-361.451	-373.558	12.107
100	B052	-361.453	-364.966	3.513
100	B053	-373.728	-353.920	-19.808
100	B054	-360.225	-367.421	7.196
100	B055	-368.823	-361.284	-7.539
100	B056	-362.682	-361.284	-1.398
100	B057	-371.279	-372.330	1.051
100	B058	-363.905	-358.829	-5.076
100	B059	-374.963	-368.648	-6.315
100	B060	-365.137	-362.511	-2.626
100	B061	-365.138	-371.103	5.965
100	B062	-368.817	-362.616	-6.201
100	B063	-363.909	-374.785	10.876
100	B064	-371.277	-364.966	-6.311
	Max	-354.088	-353.920	12.107
	Average	-366.351	-365.878	-0.473
	Min	-379.873	-378.467	-19.808
	Std Dev	5.290	5.762	7.139



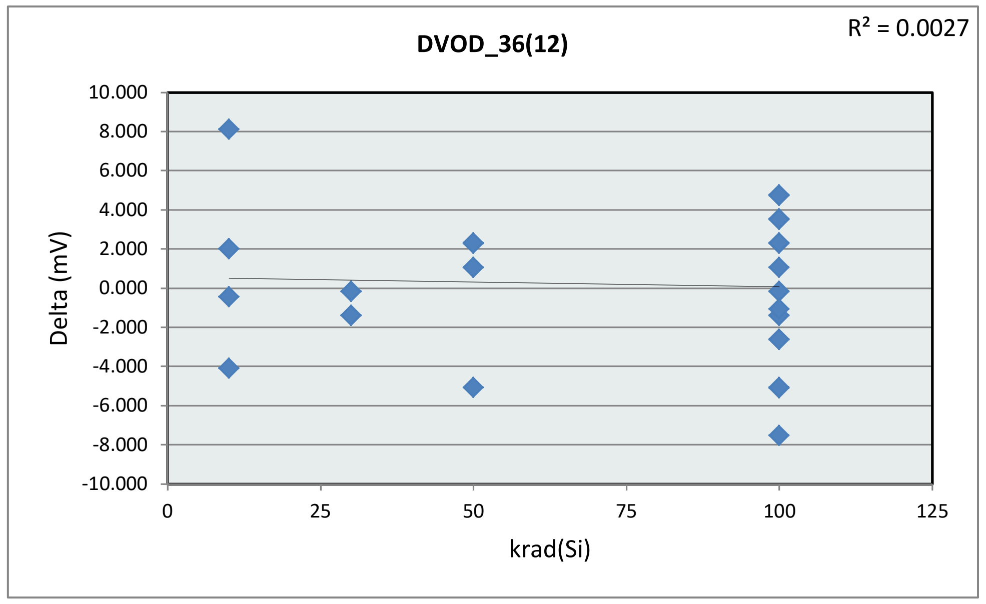
	VODL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-377.294	-372.330	-364.966	-378.467
Average	-365.557	-366.684	-362.266	-366.589
Max	-358.974	-357.602	-358.829	-353.920
UL	-320.000	-320.000	-320.000	-320.000



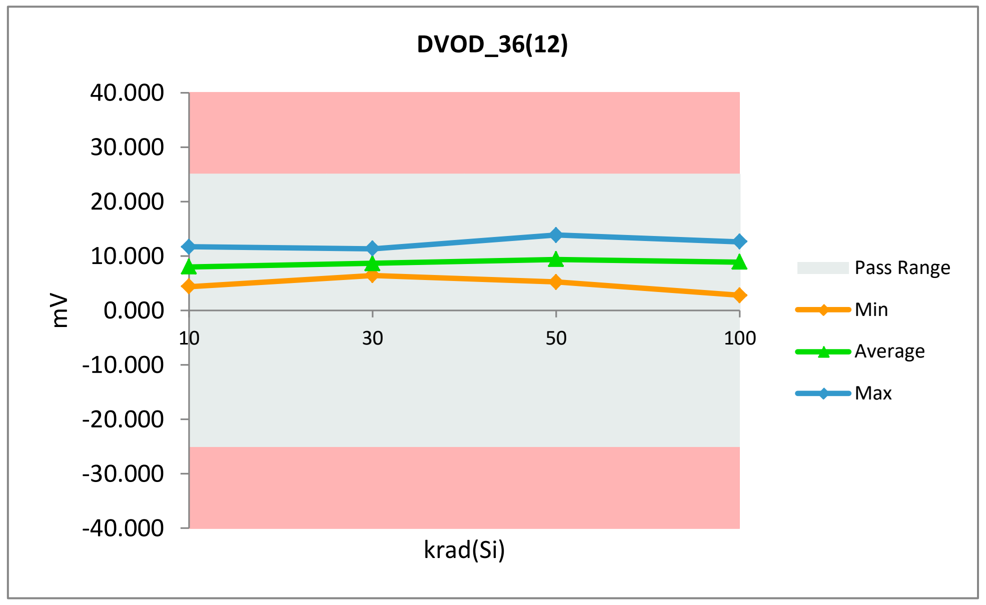
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVOD_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	12.510	4.409	8.101
10	7	7.593	8.047	-0.454
10	8	11.277	9.281	1.996
10	9	7.585	11.688	-4.103
10	10	8.827	6.828	1.999
30	6	6.307	6.480	-0.173
30	7	6.313	6.480	-0.167
30	8	9.998	11.390	-1.392
30	9	8.771	10.162	-1.391
30	10	7.527	8.935	-1.408
50	16	7.537	5.253	2.284
50	17	8.761	13.845	-5.084
50	18	8.767	7.708	1.059
50	19	12.458	10.162	2.296
50	20	11.221	10.162	1.059
100	B043	11.225	7.707	3.518
100	B044	3.851	11.389	-7.538
100	B045	5.076	6.480	-1.404
100	B046	5.070	10.162	-5.092
100	B047	7.525	2.798	4.727
100	B048	8.764	5.253	3.511
100	B049	6.314	11.390	-5.076
100	B050	9.986	6.480	3.506
100	B051	7.547	10.162	-2.615
100	B052	9.999	11.390	-1.391
100	B053	10.001	5.253	4.748
100	B054	8.772	11.389	-2.617
100	B055	5.081	7.708	-2.627
100	B056	9.996	10.162	-0.166
100	B057	12.445	10.162	2.283
100	B058	12.461	10.162	2.299
100	B059	9.987	5.253	4.734
100	B060	9.996	8.935	1.061
100	B061	12.449	12.617	-0.168
100	B062	10.002	11.064	-1.063
100	B063	7.542	10.162	-2.620
100	B064	14.904	10.162	4.742
	Max	14.904	13.845	8.101
	Average	9.039	8.840	0.199
	Min	3.851	2.798	-7.538
	Std Dev	2.512	2.587	3.388

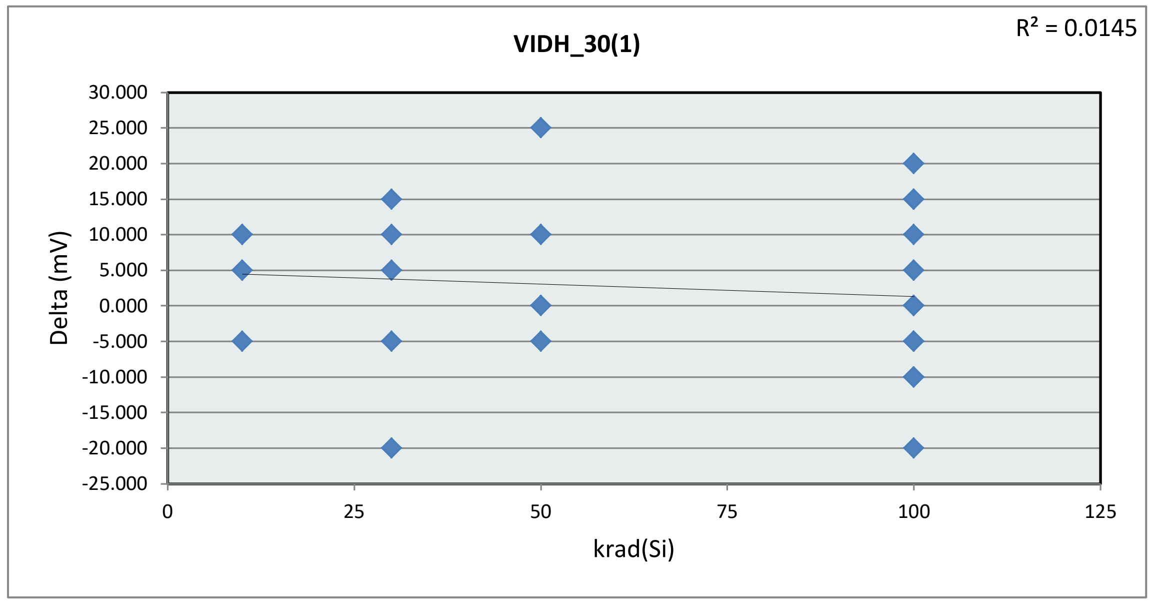


	DVOD_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	4.409	6.480	5.253	2.798
Average	8.051	8.689	9.426	8.920
Max	11.688	11.390	13.845	12.617
UL	25.000	25.000	25.000	25.000

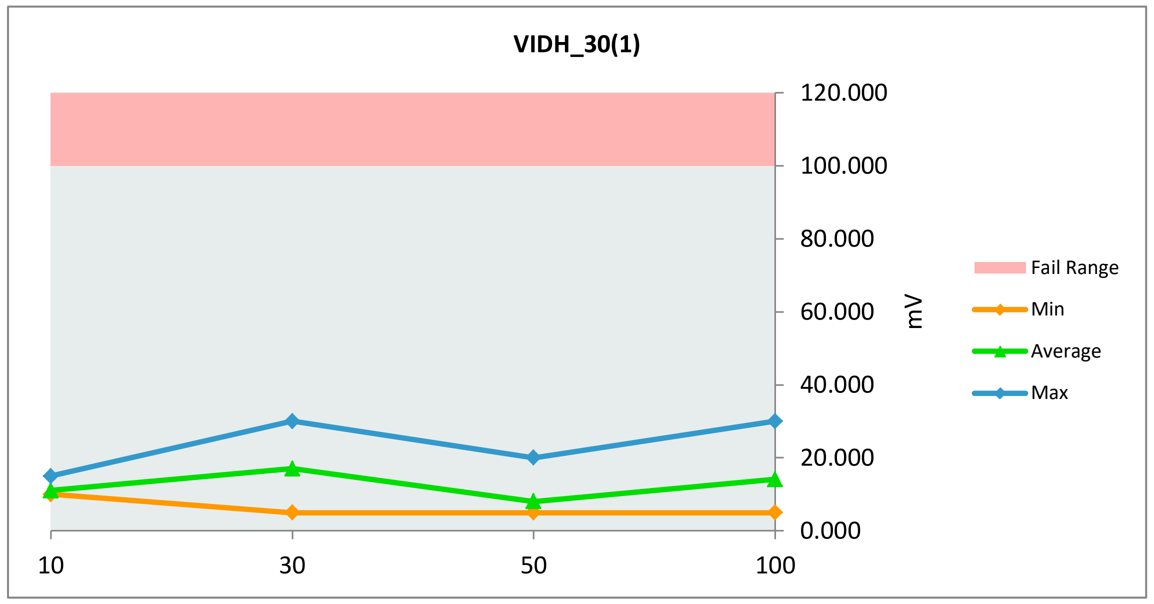


TID Report
SN55LVCP22A-SP

		VIDH_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	25.000	15.000	10.000
10	7	5.000	10.000	-5.000
10	8	15.000	10.000	5.000
10	9	15.000	10.000	5.000
10	10	20.000	10.000	10.000
30	6	5.000	10.000	-5.000
30	7	35.000	30.000	5.000
30	8	20.000	5.000	15.000
30	9	25.000	15.000	10.000
30	10	5.000	25.000	-20.000
50	16	15.000	20.000	-5.000
50	17	5.000	5.000	0.000
50	18	5.000	5.000	0.000
50	19	30.000	5.000	25.000
50	20	15.000	5.000	10.000
100	B043	20.000	5.000	15.000
100	B044	25.000	5.000	20.000
100	B045	15.000	5.000	10.000
100	B046	15.000	20.000	-5.000
100	B047	5.000	25.000	-20.000
100	B048	5.000	15.000	-10.000
100	B049	15.000	20.000	-5.000
100	B050	5.000	15.000	-10.000
100	B051	20.000	5.000	15.000
100	B052	5.000	5.000	0.000
100	B053	15.000	15.000	0.000
100	B054	25.000	5.000	20.000
100	B055	15.000	20.000	-5.000
100	B056	20.000	15.000	5.000
100	B057	5.000	15.000	-10.000
100	B058	25.000	30.000	-5.000
100	B059	5.000	5.000	0.000
100	B060	25.000	20.000	5.000
100	B061	5.000	5.000	0.000
100	B062	20.000	30.000	-10.000
100	B063	20.000	5.000	15.000
100	B064	25.000	25.000	0.000
	Max	35.000	30.000	25.000
	Average	15.541	13.243	2.297
	Min	5.000	5.000	-20.000
	Std Dev	8.643	8.351	10.710

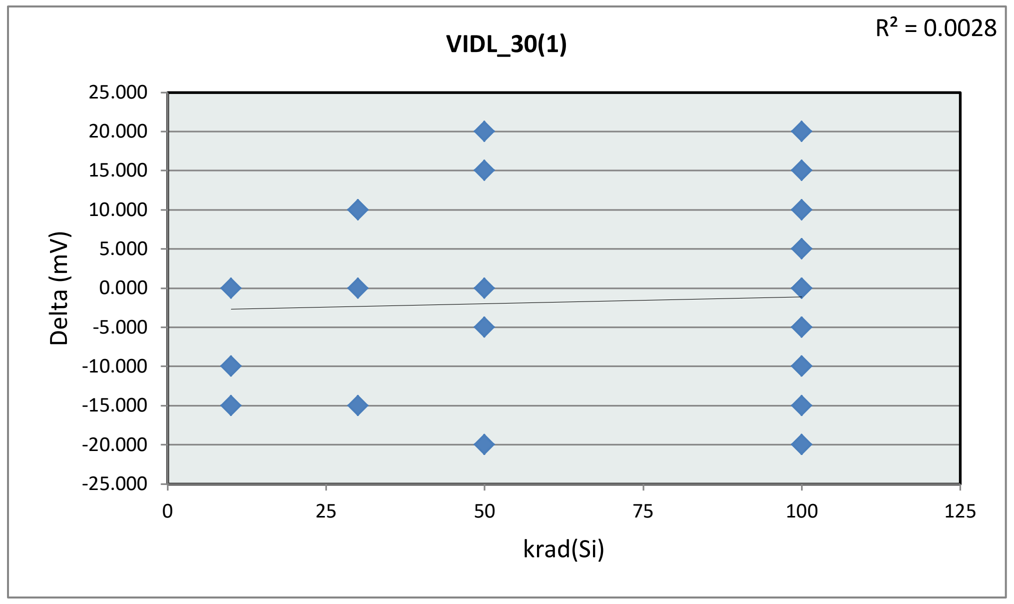


	VIDH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	11.000	17.000	8.000	14.091
Max	15.000	30.000	20.000	30.000
UL	100.000	100.000	100.000	100.000

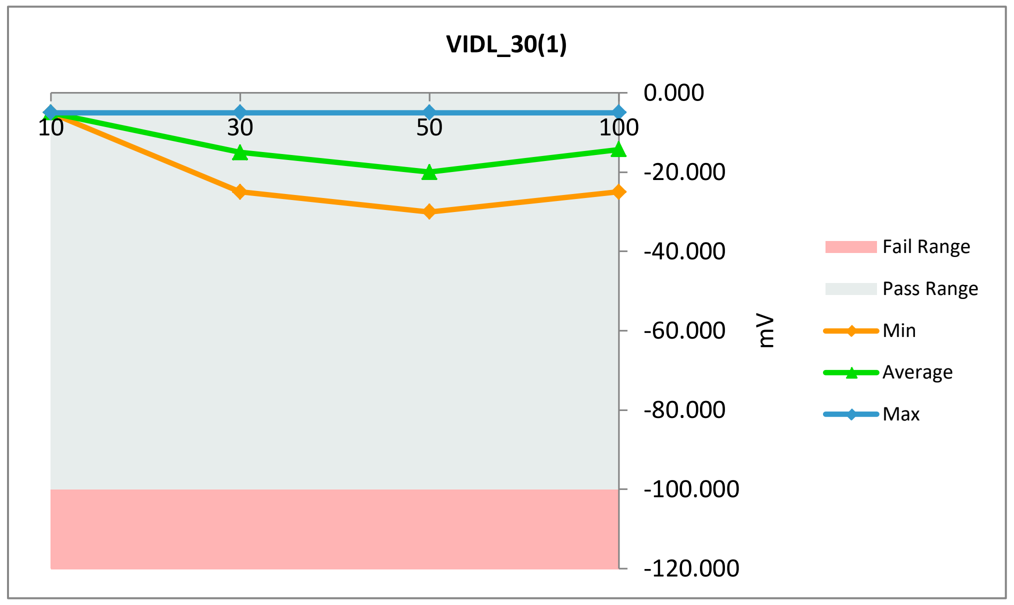


TID Report
SN55LVCP22A-SP

		VIDL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-20.000	-5.000	-15.000
10	8	-15.000	-5.000	-10.000
10	9	-15.000	-5.000	-10.000
10	10	-5.000	-5.000	0.000
30	6	-15.000	-15.000	0.000
30	7	-5.000	-15.000	10.000
30	8	-15.000	-25.000	10.000
30	9	-5.000	-15.000	10.000
30	10	-20.000	-5.000	-15.000
50	16	-10.000	-5.000	-5.000
50	17	-30.000	-30.000	0.000
50	18	-30.000	-10.000	-20.000
50	19	-5.000	-25.000	20.000
50	20	-15.000	-30.000	15.000
100	B043	-25.000	-25.000	0.000
100	B044	-5.000	-25.000	20.000
100	B045	-15.000	-5.000	-10.000
100	B046	-15.000	-25.000	10.000
100	B047	-25.000	-5.000	-20.000
100	B048	-15.000	-5.000	-10.000
100	B049	-20.000	-25.000	5.000
100	B050	-25.000	-15.000	-10.000
100	B051	-5.000	-20.000	15.000
100	B052	-10.000	-10.000	0.000
100	B053	-10.000	-20.000	10.000
100	B054	-25.000	-25.000	0.000
100	B055	-15.000	-5.000	-10.000
100	B056	-5.000	-10.000	5.000
100	B057	-25.000	-5.000	-20.000
100	B058	-5.000	-20.000	15.000
100	B059	-20.000	-15.000	-5.000
100	B060	-10.000	-5.000	-5.000
100	B061	-30.000	-25.000	-5.000
100	B062	-20.000	-5.000	-15.000
100	B063	-15.000	-15.000	0.000
100	B064	-15.000	-5.000	-10.000
	Max	-5.000	-5.000	20.000
	Average	-15.541	-13.919	-1.622
	Min	-30.000	-30.000	-20.000
	Std Dev	7.798	8.908	11.429



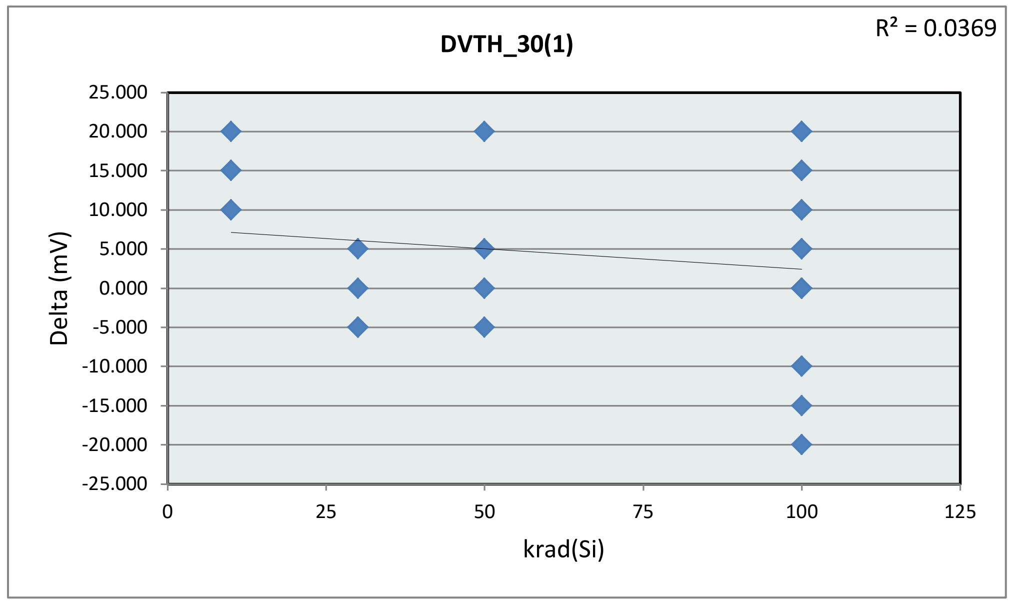
	VIDL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-25.000	-30.000	-25.000
Average	-5.000	-15.000	-20.000	-14.318
Max	-5.000	-5.000	-5.000	-5.000
UL				



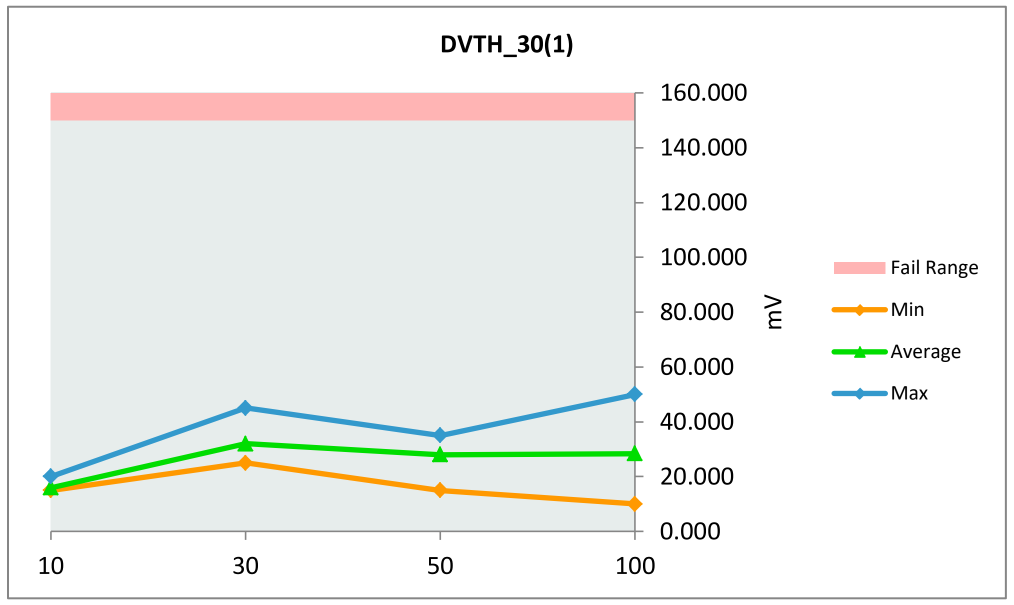
TID Report
SN55LVCP22A-SP

	DVTH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	40.000	20.000	20.000
10	7	25.000	15.000	10.000
10	8	30.000	15.000	15.000
10	9	30.000	15.000	15.000
10	10	25.000	15.000	10.000
30	6	20.000	25.000	-5.000
30	7	40.000	45.000	-5.000
30	8	35.000	30.000	5.000
30	9	30.000	30.000	0.000
30	10	25.000	30.000	-5.000
50	16	25.000	25.000	0.000
50	17	35.000	35.000	0.000
50	18	35.000	15.000	20.000
50	19	35.000	30.000	5.000
50	20	30.000	35.000	-5.000
100	B043	45.000	30.000	15.000
100	B044	30.000	30.000	0.000
100	B045	30.000	10.000	20.000
100	B046	30.000	45.000	-15.000
100	B047	30.000	30.000	0.000
100	B048	20.000	20.000	0.000
100	B049	35.000	45.000	-10.000
100	B050	30.000	30.000	0.000
100	B051	25.000	25.000	0.000
100	B052	15.000	15.000	0.000
100	B053	25.000	35.000	-10.000
100	B054	50.000	30.000	20.000
100	B055	30.000	25.000	5.000
100	B056	25.000	25.000	0.000
100	B057	30.000	20.000	10.000
100	B058	30.000	50.000	-20.000
100	B059	25.000	20.000	5.000
100	B060	35.000	25.000	10.000
100	B061	35.000	30.000	5.000
100	B062	40.000	35.000	5.000
100	B063	35.000	20.000	15.000
100	B064	40.000	30.000	10.000
	Max	50.000	50.000	20.000
	Average	31.081	27.162	3.919
	Min	15.000	10.000	-20.000
	Std Dev	7.084	9.541	9.870

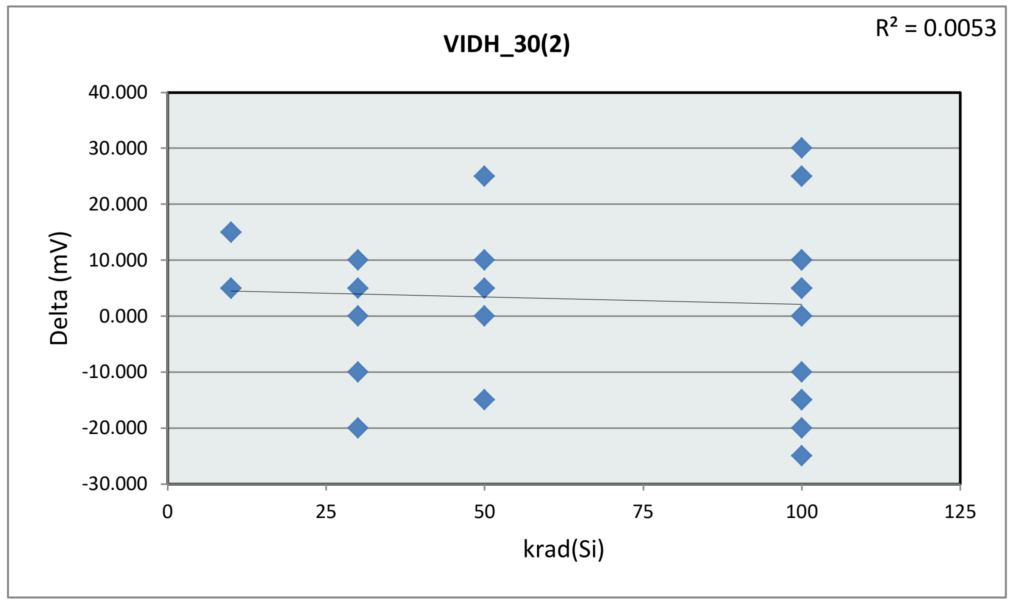


	DVTH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	15.000	10.000
Average	16.000	32.000	28.000	28.409
Max	20.000	45.000	35.000	50.000
UL	150.000	150.000	150.000	150.000

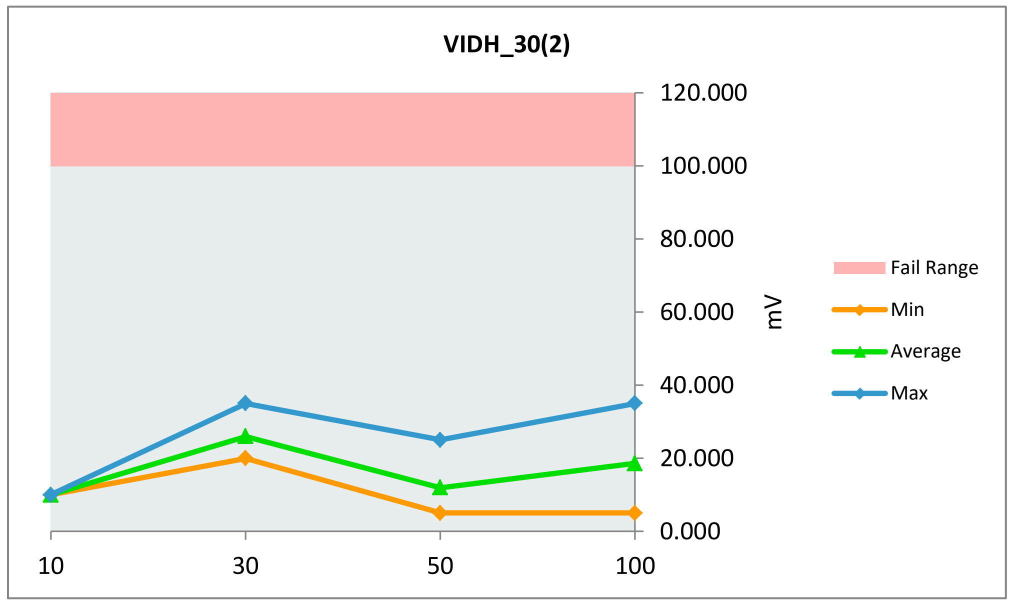


TID Report
SN55LVCP22A-SP

		VIDH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	25.000	10.000	15.000
10	7	15.000	10.000	5.000
10	8	15.000	10.000	5.000
10	9	25.000	10.000	15.000
10	10	15.000	10.000	5.000
30	6	25.000	20.000	5.000
30	7	30.000	30.000	0.000
30	8	30.000	20.000	10.000
30	9	25.000	35.000	-10.000
30	10	5.000	25.000	-20.000
50	16	25.000	20.000	5.000
50	17	15.000	5.000	10.000
50	18	10.000	25.000	-15.000
50	19	30.000	5.000	25.000
50	20	5.000	5.000	0.000
100	B043	30.000	5.000	25.000
100	B044	20.000	10.000	10.000
100	B045	5.000	20.000	-15.000
100	B046	5.000	30.000	-25.000
100	B047	5.000	20.000	-15.000
100	B048	15.000	5.000	10.000
100	B049	25.000	20.000	5.000
100	B050	5.000	5.000	0.000
100	B051	30.000	5.000	25.000
100	B052	25.000	15.000	10.000
100	B053	5.000	25.000	-20.000
100	B054	35.000	5.000	30.000
100	B055	30.000	30.000	0.000
100	B056	25.000	20.000	5.000
100	B057	20.000	15.000	5.000
100	B058	20.000	35.000	-15.000
100	B059	30.000	25.000	5.000
100	B060	35.000	25.000	10.000
100	B061	20.000	15.000	5.000
100	B062	20.000	20.000	0.000
100	B063	20.000	30.000	-10.000
100	B064	35.000	30.000	5.000
	Max	35.000	35.000	30.000
	Average	20.405	17.568	2.838
	Min	5.000	5.000	-25.000
	Std Dev	9.674	9.619	13.257

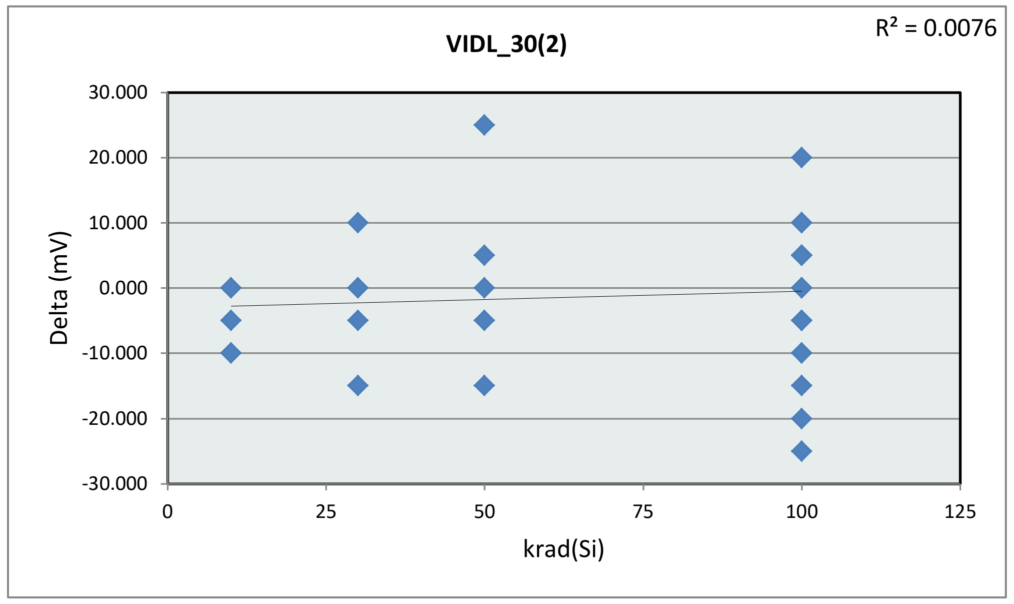


	VIDH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	5.000	5.000
Average	10.000	26.000	12.000	18.636
Max	10.000	35.000	25.000	35.000
UL	100.000	100.000	100.000	100.000

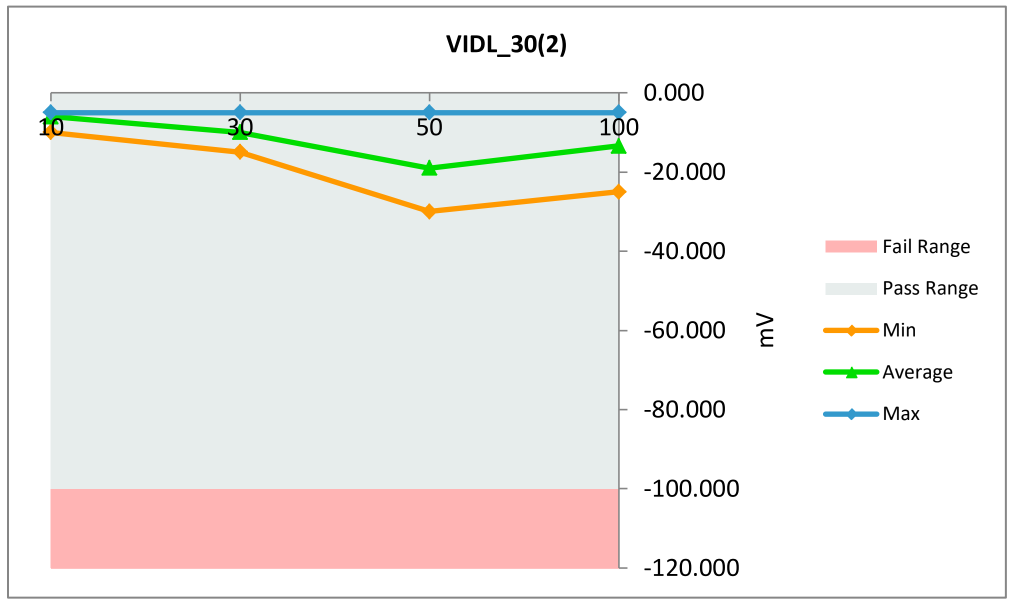


TID Report
SN55LVCP22A-SP

		VIDL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-15.000	-5.000	-10.000
10	8	-15.000	-5.000	-10.000
10	9	-5.000	-5.000	0.000
10	10	-10.000	-10.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-15.000	-15.000	0.000
30	8	-5.000	-15.000	10.000
30	9	-10.000	-5.000	-5.000
30	10	-25.000	-10.000	-15.000
50	16	-5.000	-10.000	5.000
50	17	-30.000	-30.000	0.000
50	18	-20.000	-5.000	-15.000
50	19	-5.000	-30.000	25.000
50	20	-25.000	-20.000	-5.000
100	B043	-20.000	-25.000	5.000
100	B044	-10.000	-20.000	10.000
100	B045	-25.000	-5.000	-20.000
100	B046	-20.000	-20.000	0.000
100	B047	-30.000	-5.000	-25.000
100	B048	-15.000	-20.000	5.000
100	B049	-10.000	-20.000	10.000
100	B050	-25.000	-20.000	-5.000
100	B051	-5.000	-25.000	20.000
100	B052	-5.000	-15.000	10.000
100	B053	-25.000	-10.000	-15.000
100	B054	-15.000	-20.000	5.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-15.000	-20.000	5.000
100	B058	-10.000	-15.000	5.000
100	B059	-10.000	-5.000	-5.000
100	B060	-5.000	-5.000	0.000
100	B061	-20.000	-10.000	-10.000
100	B062	-20.000	-15.000	-5.000
100	B063	-15.000	-5.000	-10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-13.919	-12.703	-1.216
	Min	-30.000	-30.000	-25.000
	Std Dev	8.005	7.958	10.234

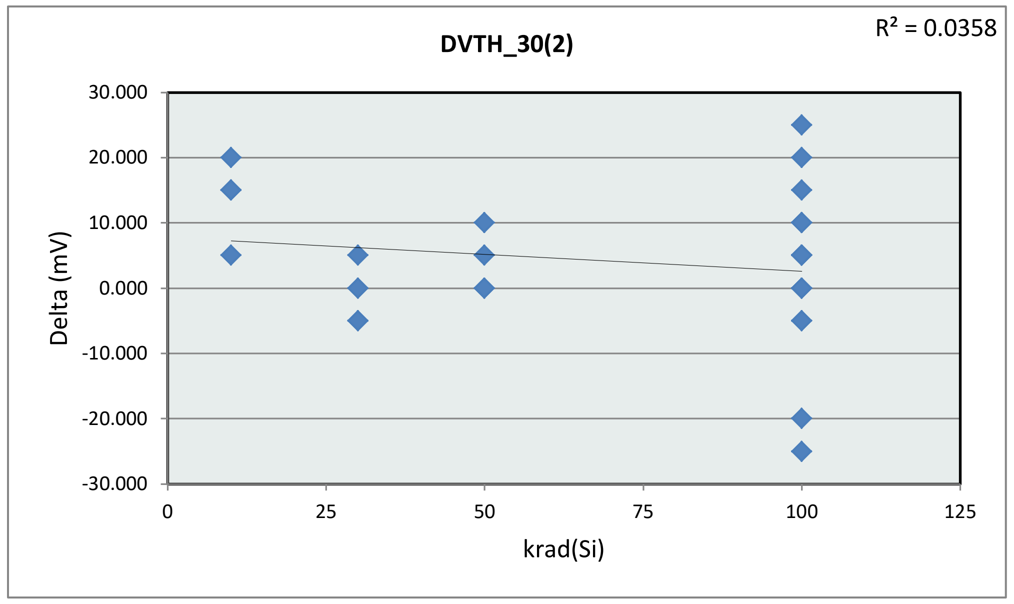


	VIDL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-10.000	-15.000	-30.000	-25.000
Average	-6.000	-10.000	-19.000	-13.409
Max	-5.000	-5.000	-5.000	-5.000
UL				

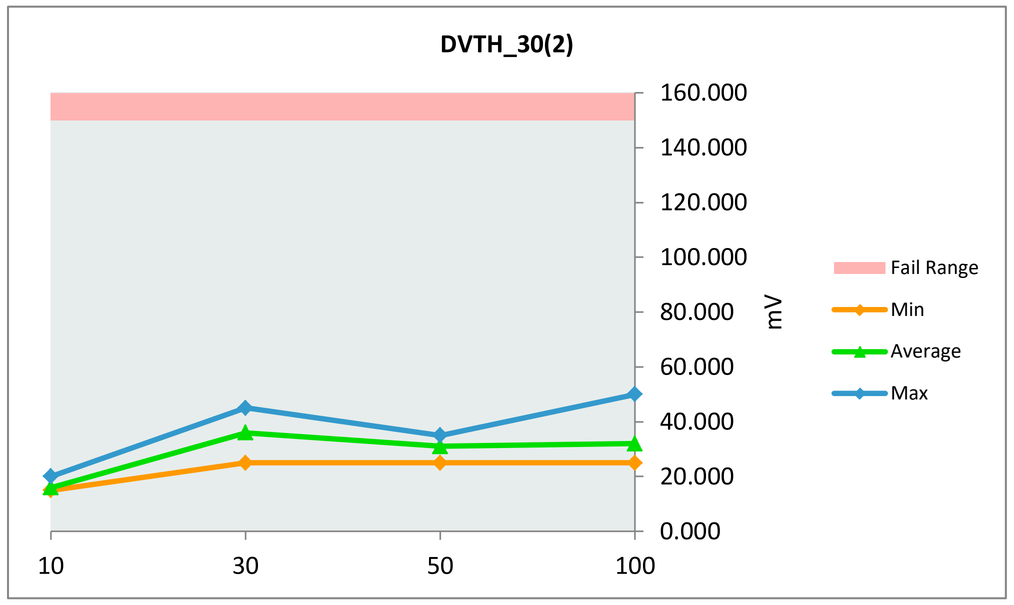


TID Report
SN55LVCP22A-SP

		DVTH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	35.000	15.000	20.000
10	7	30.000	15.000	15.000
10	8	30.000	15.000	15.000
10	9	30.000	15.000	15.000
10	10	25.000	20.000	5.000
30	6	30.000	25.000	5.000
30	7	45.000	45.000	0.000
30	8	35.000	35.000	0.000
30	9	35.000	40.000	-5.000
30	10	30.000	35.000	-5.000
50	16	30.000	30.000	0.000
50	17	45.000	35.000	10.000
50	18	30.000	30.000	0.000
50	19	35.000	35.000	0.000
50	20	30.000	25.000	5.000
100	B043	50.000	30.000	20.000
100	B044	30.000	30.000	0.000
100	B045	30.000	25.000	5.000
100	B046	25.000	50.000	-25.000
100	B047	35.000	25.000	10.000
100	B048	30.000	25.000	5.000
100	B049	35.000	40.000	-5.000
100	B050	30.000	25.000	5.000
100	B051	35.000	30.000	5.000
100	B052	30.000	30.000	0.000
100	B053	30.000	35.000	-5.000
100	B054	50.000	25.000	25.000
100	B055	35.000	35.000	0.000
100	B056	30.000	25.000	5.000
100	B057	35.000	35.000	0.000
100	B058	30.000	50.000	-20.000
100	B059	40.000	30.000	10.000
100	B060	40.000	30.000	10.000
100	B061	40.000	25.000	15.000
100	B062	40.000	35.000	5.000
100	B063	35.000	35.000	0.000
100	B064	40.000	35.000	5.000
	Max	50.000	50.000	25.000
	Average	34.324	30.270	4.054
	Min	25.000	15.000	-25.000
	Std Dev	6.142	8.656	9.849

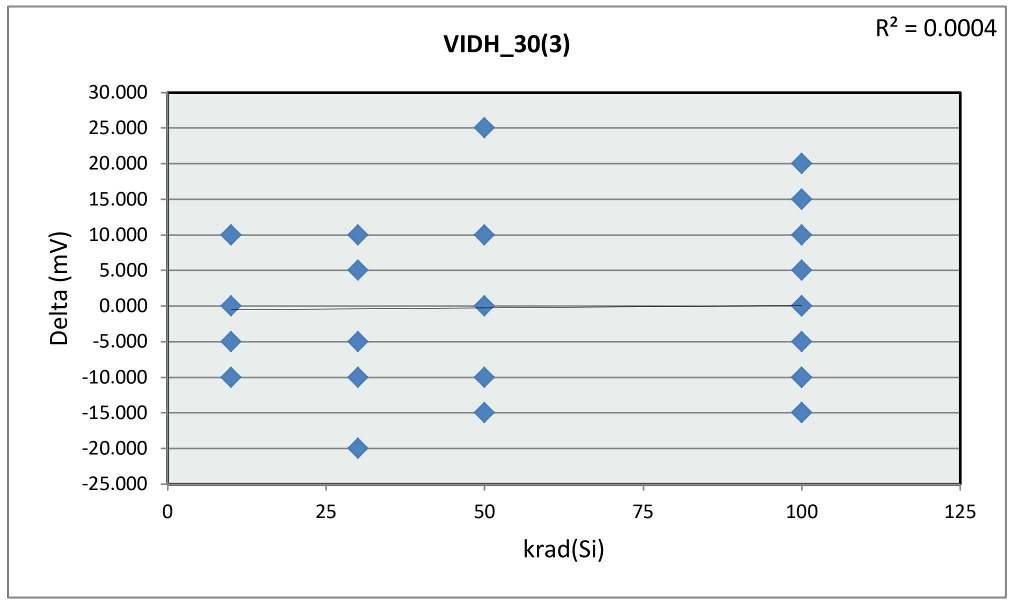


	DVTH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	25.000	25.000
Average	16.000	36.000	31.000	32.045
Max	20.000	45.000	35.000	50.000
UL	150.000	150.000	150.000	150.000

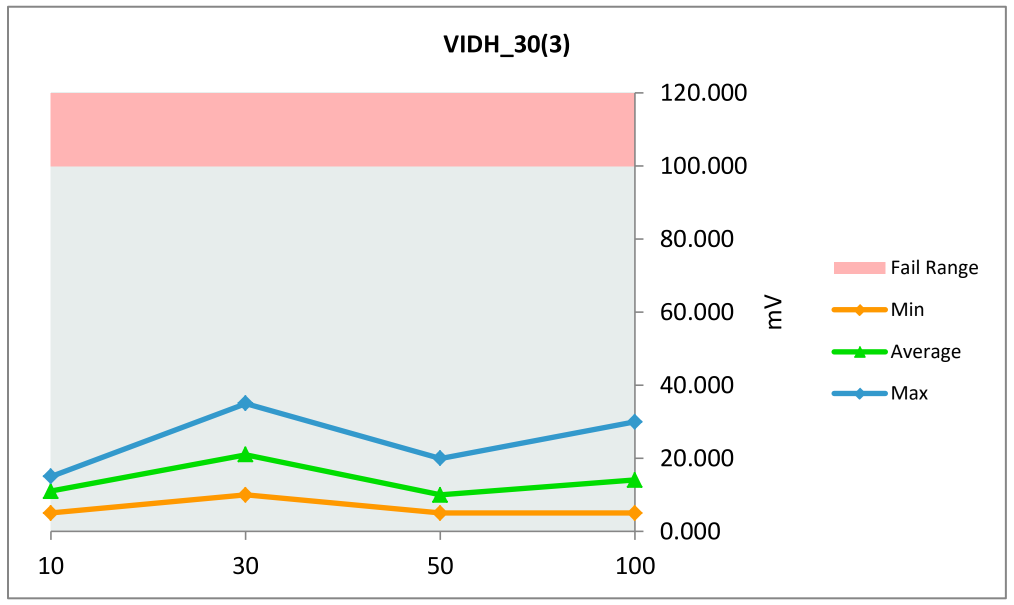


TID Report
SN55LVCP22A-SP

		VIDH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	25.000	15.000	10.000
10	7	10.000	10.000	0.000
10	8	5.000	10.000	-5.000
10	9	5.000	15.000	-10.000
10	10	15.000	5.000	10.000
30	6	5.000	15.000	-10.000
30	7	30.000	35.000	-5.000
30	8	20.000	10.000	10.000
30	9	25.000	20.000	5.000
30	10	5.000	25.000	-20.000
50	16	5.000	20.000	-15.000
50	17	5.000	5.000	0.000
50	18	5.000	15.000	-10.000
50	19	30.000	5.000	25.000
50	20	15.000	5.000	10.000
100	B043	20.000	5.000	15.000
100	B044	25.000	5.000	20.000
100	B045	5.000	15.000	-10.000
100	B046	15.000	20.000	-5.000
100	B047	10.000	25.000	-15.000
100	B048	5.000	15.000	-10.000
100	B049	15.000	15.000	0.000
100	B050	5.000	15.000	-10.000
100	B051	20.000	5.000	15.000
100	B052	5.000	5.000	0.000
100	B053	15.000	15.000	0.000
100	B054	25.000	5.000	20.000
100	B055	5.000	20.000	-15.000
100	B056	20.000	5.000	15.000
100	B057	5.000	15.000	-10.000
100	B058	25.000	25.000	0.000
100	B059	5.000	5.000	0.000
100	B060	25.000	20.000	5.000
100	B061	5.000	5.000	0.000
100	B062	15.000	30.000	-15.000
100	B063	20.000	10.000	10.000
100	B064	20.000	30.000	-10.000
	Max	30.000	35.000	25.000
	Average	13.919	14.054	-0.135
	Min	5.000	5.000	-20.000
	Std Dev	8.671	8.403	11.576

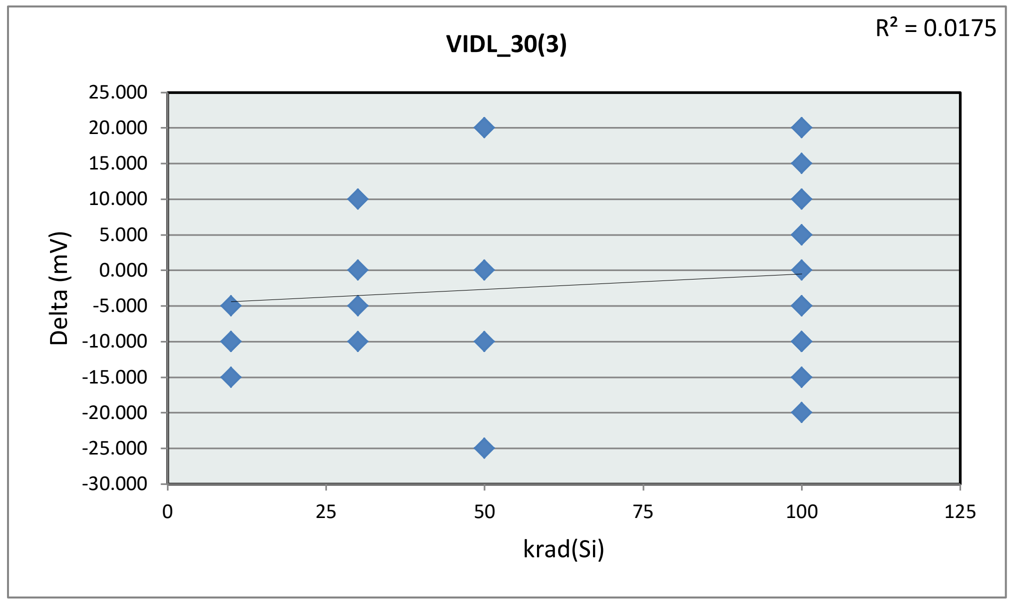


	VIDH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	10.000	5.000	5.000
Average	11.000	21.000	10.000	14.091
Max	15.000	35.000	20.000	30.000
UL	100.000	100.000	100.000	100.000

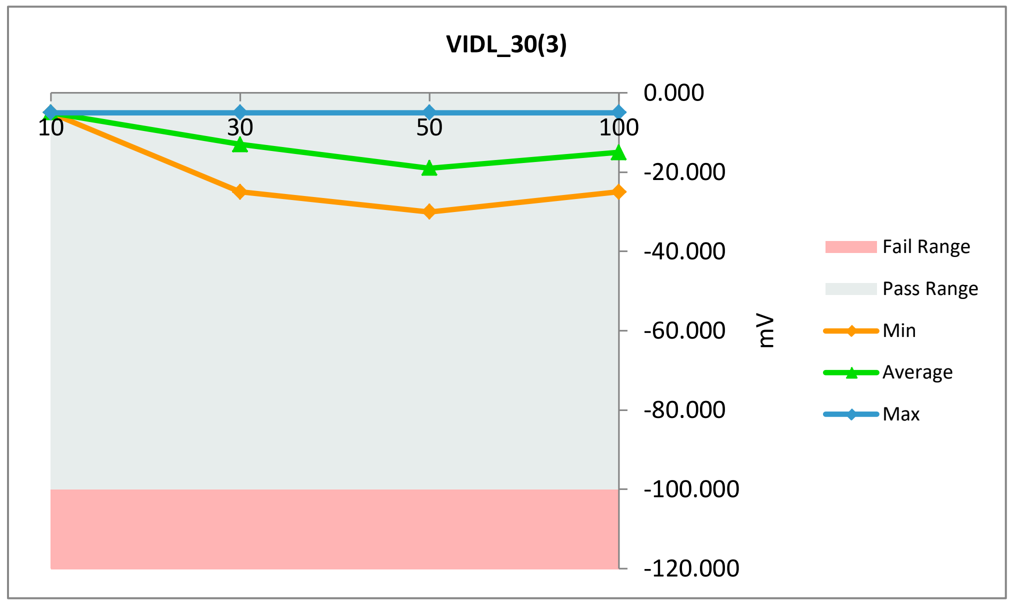


TID Report
SN55LVCP22A-SP

		VIDL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-20.000	-5.000	-15.000
10	8	-15.000	-5.000	-10.000
10	9	-15.000	-5.000	-10.000
10	10	-10.000	-5.000	-5.000
30	6	-10.000	-5.000	-5.000
30	7	-15.000	-15.000	0.000
30	8	-15.000	-25.000	10.000
30	9	-5.000	-15.000	10.000
30	10	-15.000	-5.000	-10.000
50	16	-15.000	-5.000	-10.000
50	17	-30.000	-30.000	0.000
50	18	-30.000	-5.000	-25.000
50	19	-5.000	-25.000	20.000
50	20	-10.000	-30.000	20.000
100	B043	-30.000	-25.000	-5.000
100	B044	-5.000	-25.000	20.000
100	B045	-15.000	-5.000	-10.000
100	B046	-15.000	-25.000	10.000
100	B047	-25.000	-5.000	-20.000
100	B048	-15.000	-10.000	-5.000
100	B049	-20.000	-20.000	0.000
100	B050	-25.000	-15.000	-10.000
100	B051	-5.000	-25.000	20.000
100	B052	-10.000	-15.000	5.000
100	B053	-15.000	-20.000	5.000
100	B054	-20.000	-25.000	5.000
100	B055	-15.000	-5.000	-10.000
100	B056	-5.000	-10.000	5.000
100	B057	-25.000	-10.000	-15.000
100	B058	-5.000	-20.000	15.000
100	B059	-20.000	-10.000	-10.000
100	B060	-10.000	-5.000	-5.000
100	B061	-30.000	-25.000	-5.000
100	B062	-20.000	-5.000	-15.000
100	B063	-10.000	-20.000	10.000
100	B064	-15.000	-5.000	-10.000
	Max	-5.000	-5.000	20.000
	Average	-15.676	-13.919	-1.757
	Min	-30.000	-30.000	-25.000
	Std Dev	7.561	8.986	11.857

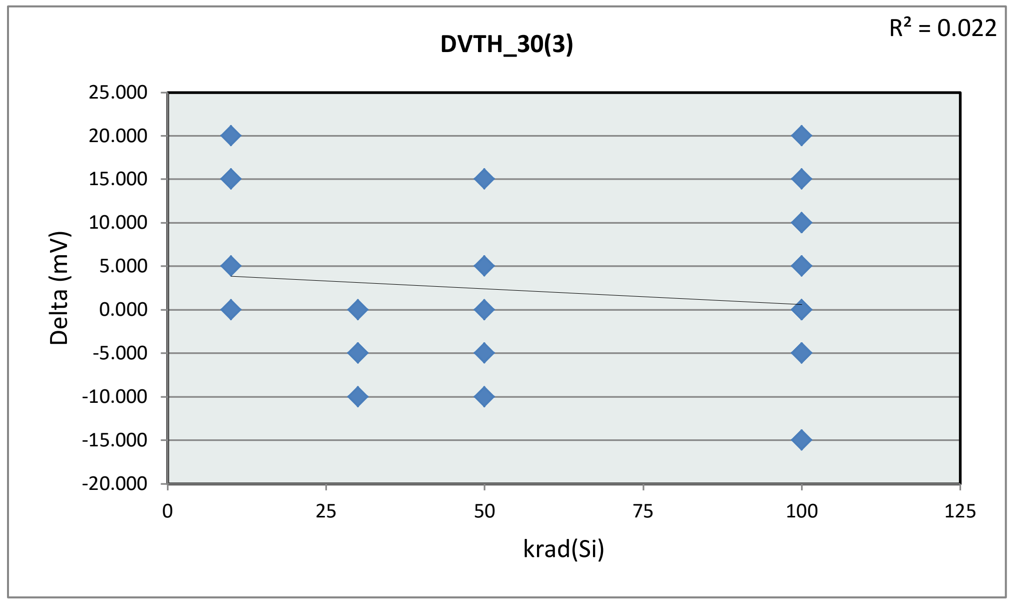


	VIDL_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-25.000	-30.000	-25.000
Average	-5.000	-13.000	-19.000	-15.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

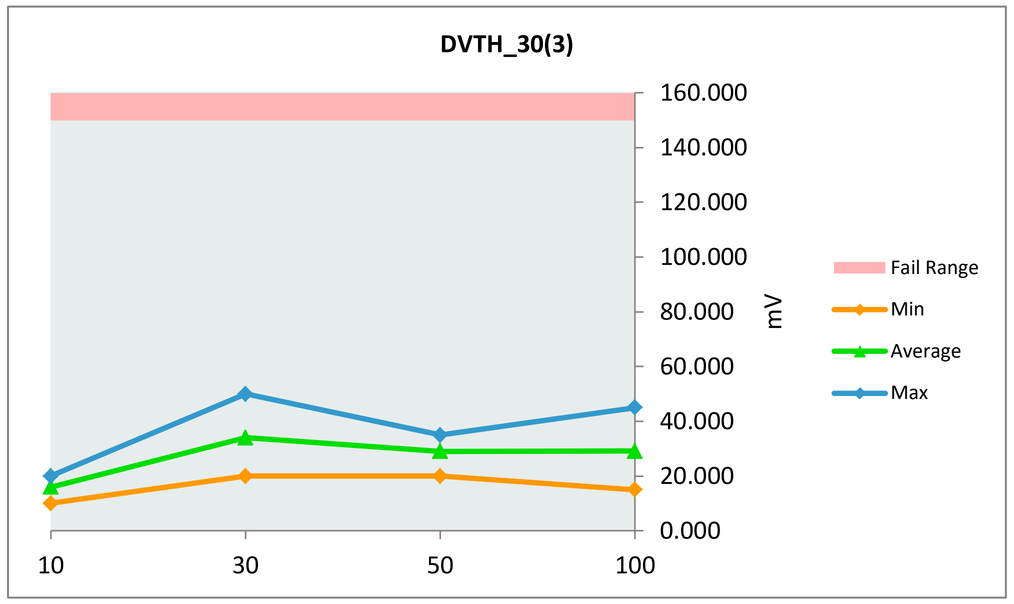


TID Report
SN55LVCP22A-SP

		DVTH_30(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		150	150	
Min Limit				
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	40.000	20.000	20.000
10	7	30.000	15.000	15.000
10	8	20.000	15.000	5.000
10	9	20.000	20.000	0.000
10	10	25.000	10.000	15.000
30	6	15.000	20.000	-5.000
30	7	45.000	50.000	-5.000
30	8	35.000	35.000	0.000
30	9	30.000	35.000	-5.000
30	10	20.000	30.000	-10.000
50	16	20.000	25.000	-5.000
50	17	35.000	35.000	0.000
50	18	35.000	20.000	15.000
50	19	35.000	30.000	5.000
50	20	25.000	35.000	-10.000
100	B043	50.000	30.000	20.000
100	B044	30.000	30.000	0.000
100	B045	20.000	20.000	0.000
100	B046	30.000	45.000	-15.000
100	B047	35.000	30.000	5.000
100	B048	20.000	25.000	-5.000
100	B049	35.000	35.000	0.000
100	B050	30.000	30.000	0.000
100	B051	25.000	30.000	-5.000
100	B052	15.000	20.000	-5.000
100	B053	30.000	35.000	-5.000
100	B054	45.000	30.000	15.000
100	B055	20.000	25.000	-5.000
100	B056	25.000	15.000	10.000
100	B057	30.000	25.000	5.000
100	B058	30.000	45.000	-15.000
100	B059	25.000	15.000	10.000
100	B060	35.000	25.000	10.000
100	B061	35.000	30.000	5.000
100	B062	35.000	35.000	0.000
100	B063	30.000	30.000	0.000
100	B064	35.000	35.000	0.000
	Max	50.000	50.000	20.000
	Average	29.595	27.973	1.622
	Min	15.000	10.000	-15.000
	Std Dev	8.281	9.011	8.979



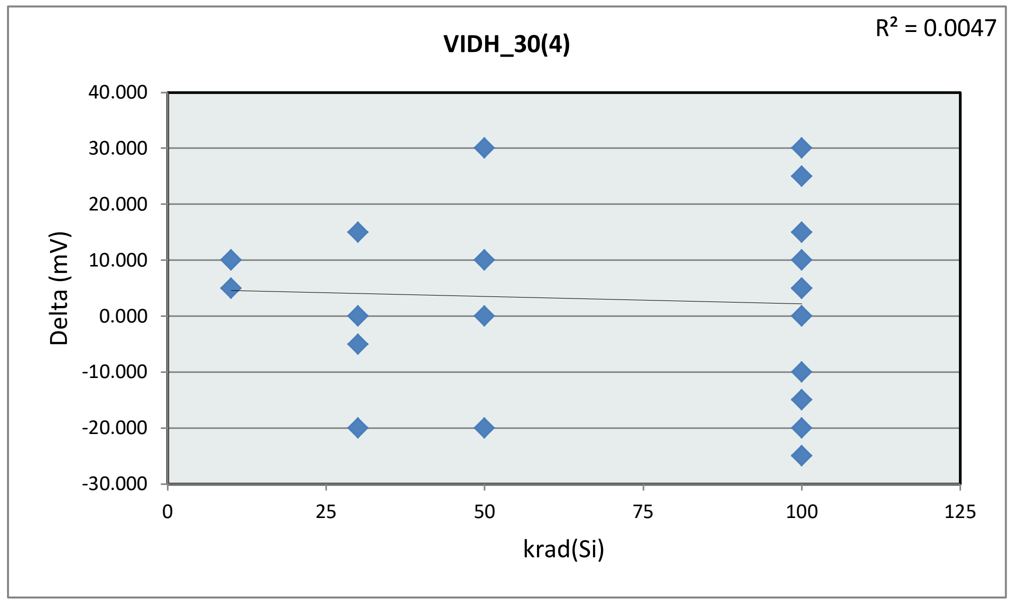
	DVTH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	20.000	15.000
Average	16.000	34.000	29.000	29.091
Max	20.000	50.000	35.000	45.000
UL	150.000	150.000	150.000	150.000



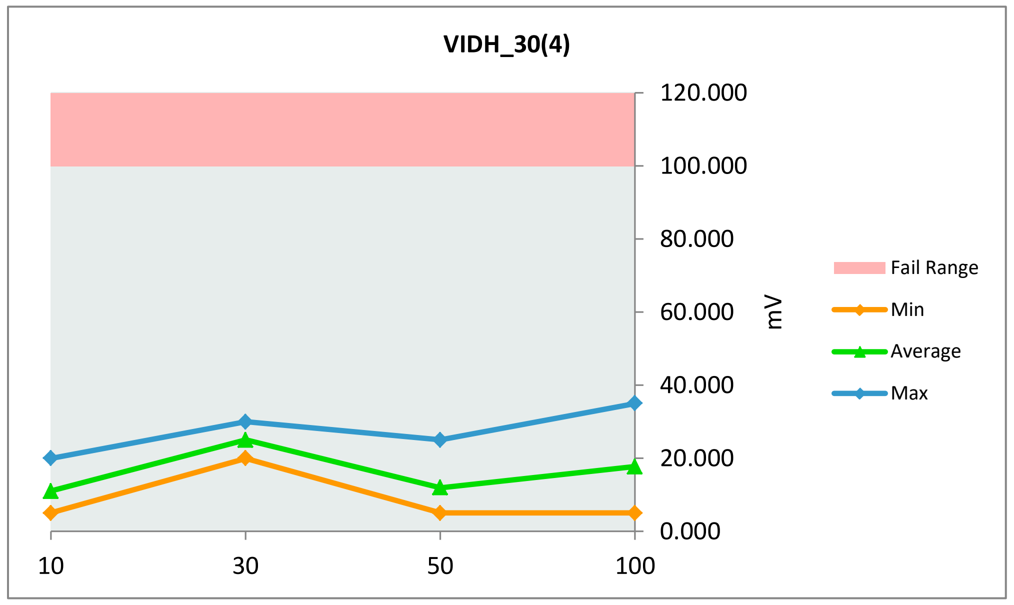
TID Report
SN55LVCP22A-SP

	VIDH_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	20.000	10.000	10.000
10	7	20.000	10.000	10.000
10	8	15.000	10.000	5.000
10	9	25.000	20.000	5.000
10	10	15.000	5.000	10.000
30	6	20.000	20.000	0.000
30	7	30.000	30.000	0.000
30	8	35.000	20.000	15.000
30	9	25.000	30.000	-5.000
30	10	5.000	25.000	-20.000
50	16	30.000	20.000	10.000
50	17	15.000	5.000	10.000
50	18	5.000	25.000	-20.000
50	19	35.000	5.000	30.000
50	20	5.000	5.000	0.000
100	B043	30.000	5.000	25.000
100	B044	20.000	5.000	15.000
100	B045	5.000	20.000	-15.000
100	B046	5.000	30.000	-25.000
100	B047	5.000	20.000	-15.000
100	B048	15.000	5.000	10.000
100	B049	25.000	20.000	5.000
100	B050	10.000	5.000	5.000
100	B051	30.000	5.000	25.000
100	B052	20.000	10.000	10.000
100	B053	5.000	25.000	-20.000
100	B054	35.000	5.000	30.000
100	B055	30.000	25.000	5.000
100	B056	25.000	20.000	5.000
100	B057	20.000	5.000	15.000
100	B058	25.000	35.000	-10.000
100	B059	30.000	25.000	5.000
100	B060	25.000	25.000	0.000
100	B061	20.000	15.000	5.000
100	B062	20.000	20.000	0.000
100	B063	5.000	30.000	-25.000
100	B064	35.000	35.000	0.000
	Max	35.000	35.000	30.000
	Average	20.000	17.027	2.973
	Min	5.000	5.000	-25.000
	Std Dev	10.069	9.962	14.262

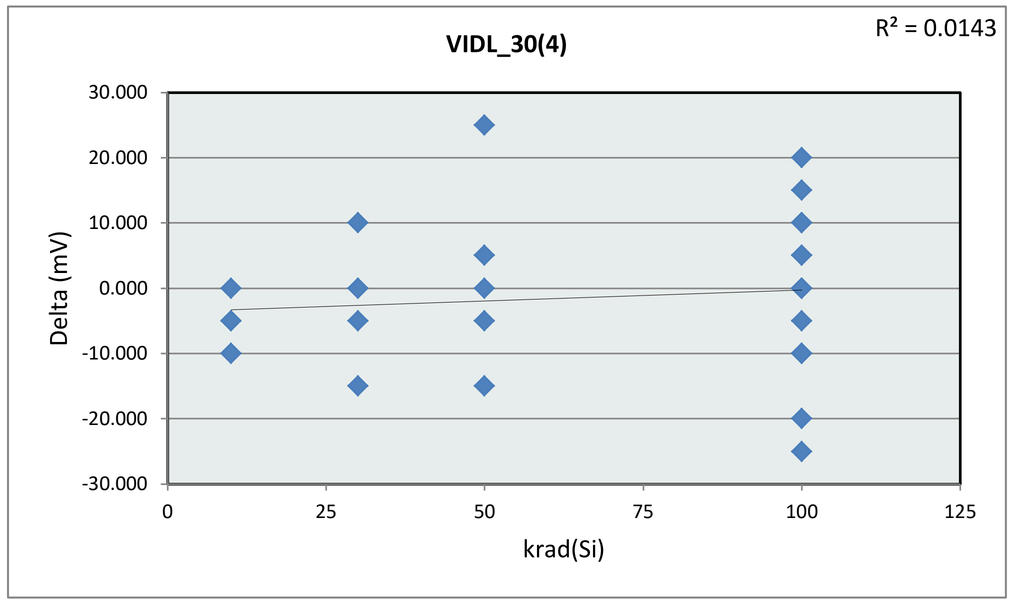


	VIDH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	20.000	5.000	5.000
Average	11.000	25.000	12.000	17.727
Max	20.000	30.000	25.000	35.000
UL	100.000	100.000	100.000	100.000

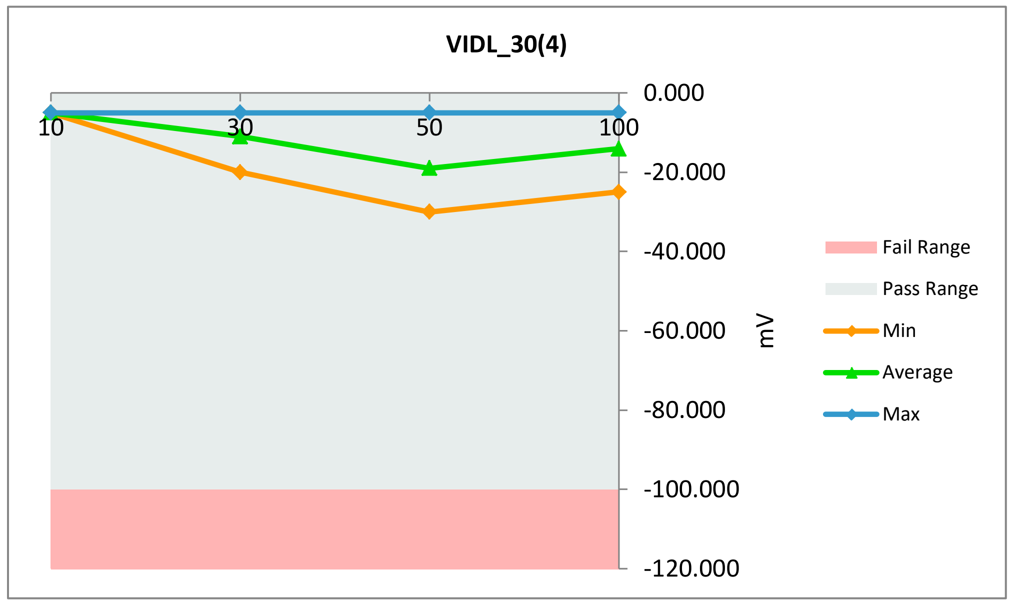


TID Report
SN55LVCP22A-SP

		VIDL_30(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	**Serial #**	**DR Unbiased LVCP**	**5 Post Test (Unbia**	**Delta**
10	6	-10.000	-5.000	-5.000
10	7	-15.000	-5.000	-10.000
10	8	-15.000	-5.000	-10.000
10	9	-5.000	-5.000	0.000
10	10	-10.000	-5.000	-5.000
30	6	-5.000	-5.000	0.000
30	7	-20.000	-20.000	0.000
30	8	-5.000	-15.000	10.000
30	9	-10.000	-5.000	-5.000
30	10	-25.000	-10.000	-15.000
50	16	-5.000	-10.000	5.000
50	17	-30.000	-30.000	0.000
50	18	-20.000	-5.000	-15.000
50	19	-5.000	-30.000	25.000
50	20	-25.000	-20.000	-5.000
100	B043	-25.000	-25.000	0.000
100	B044	-10.000	-20.000	10.000
100	B045	-25.000	-5.000	-20.000
100	B046	-20.000	-20.000	0.000
100	B047	-30.000	-5.000	-25.000
100	B048	-15.000	-25.000	10.000
100	B049	-10.000	-25.000	15.000
100	B050	-25.000	-25.000	0.000
100	B051	-5.000	-25.000	20.000
100	B052	-10.000	-15.000	5.000
100	B053	-20.000	-10.000	-10.000
100	B054	-20.000	-25.000	5.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-10.000	-20.000	10.000
100	B058	-15.000	-15.000	0.000
100	B059	-10.000	-5.000	-5.000
100	B060	-5.000	-5.000	0.000
100	B061	-20.000	-10.000	-10.000
100	B062	-20.000	-10.000	-10.000
100	B063	-15.000	-5.000	-10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-14.324	-13.108	-1.216
	Min	-30.000	-30.000	-25.000
	Std Dev	8.007	8.768	10.369

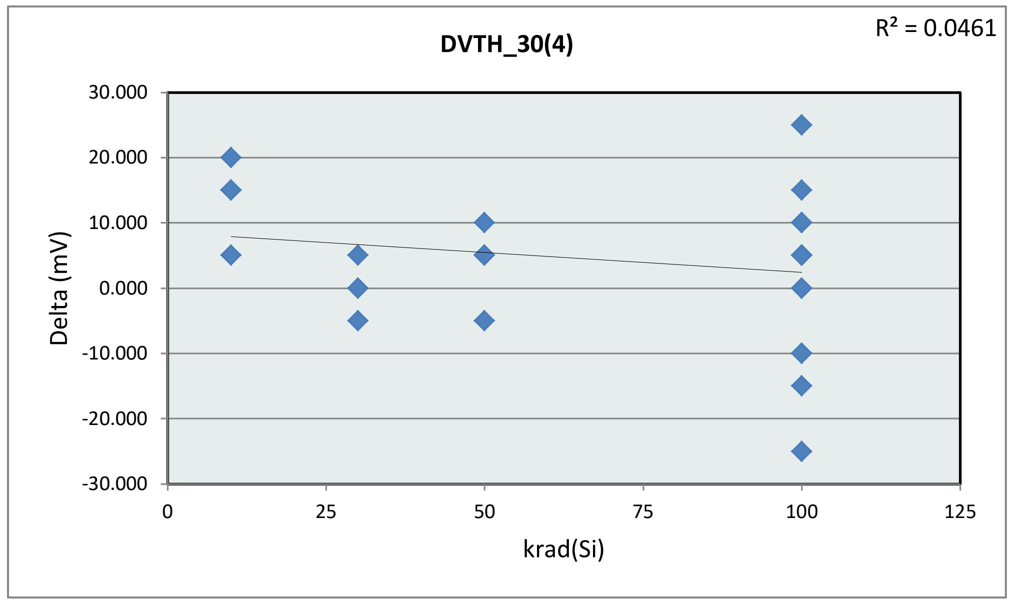


	VIDL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	**10**	**30**	**50**	**100**
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-20.000	-30.000	-25.000
Average	-5.000	-11.000	-19.000	-14.091
Max	-5.000	-5.000	-5.000	-5.000
UL				

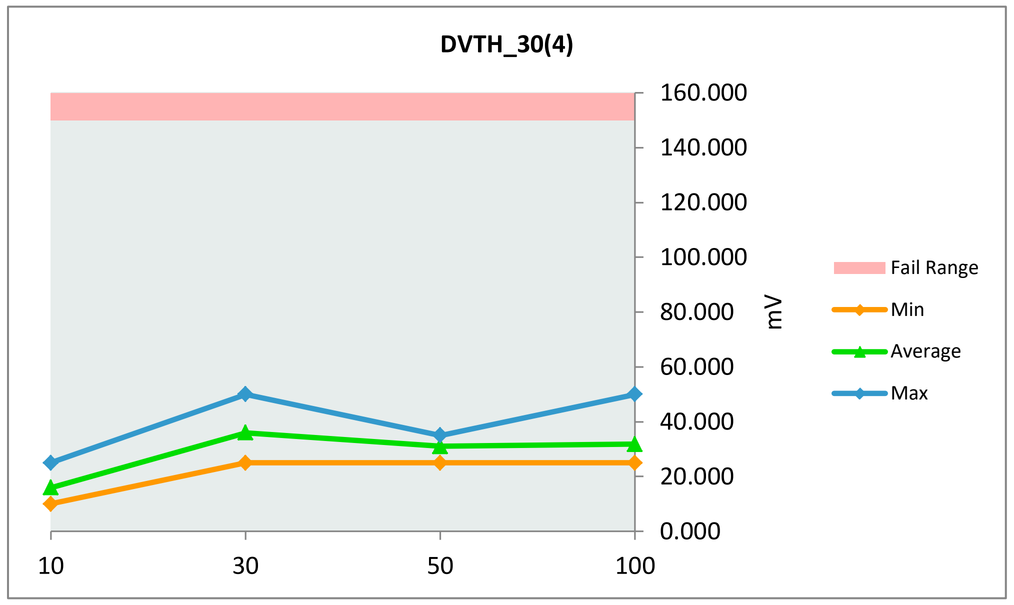


TID Report
SN55LVCP22A-SP

		DVTH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	30.000	15.000	15.000
10	7	35.000	15.000	20.000
10	8	30.000	15.000	15.000
10	9	30.000	25.000	5.000
10	10	25.000	10.000	15.000
30	6	25.000	25.000	0.000
30	7	50.000	50.000	0.000
30	8	40.000	35.000	5.000
30	9	35.000	35.000	0.000
30	10	30.000	35.000	-5.000
50	16	35.000	30.000	5.000
50	17	45.000	35.000	10.000
50	18	25.000	30.000	-5.000
50	19	40.000	35.000	5.000
50	20	30.000	25.000	5.000
100	B043	55.000	30.000	25.000
100	B044	30.000	25.000	5.000
100	B045	30.000	25.000	5.000
100	B046	25.000	50.000	-25.000
100	B047	35.000	25.000	10.000
100	B048	30.000	30.000	0.000
100	B049	35.000	45.000	-10.000
100	B050	35.000	30.000	5.000
100	B051	35.000	30.000	5.000
100	B052	30.000	25.000	5.000
100	B053	25.000	35.000	-10.000
100	B054	55.000	30.000	25.000
100	B055	35.000	30.000	5.000
100	B056	30.000	25.000	5.000
100	B057	30.000	25.000	5.000
100	B058	40.000	50.000	-10.000
100	B059	40.000	30.000	10.000
100	B060	30.000	30.000	0.000
100	B061	40.000	25.000	15.000
100	B062	40.000	30.000	10.000
100	B063	20.000	35.000	-15.000
100	B064	40.000	40.000	0.000
	Max	55.000	50.000	25.000
	Average	34.324	30.135	4.189
	Min	20.000	10.000	-25.000
	Std Dev	8.007	9.166	10.309

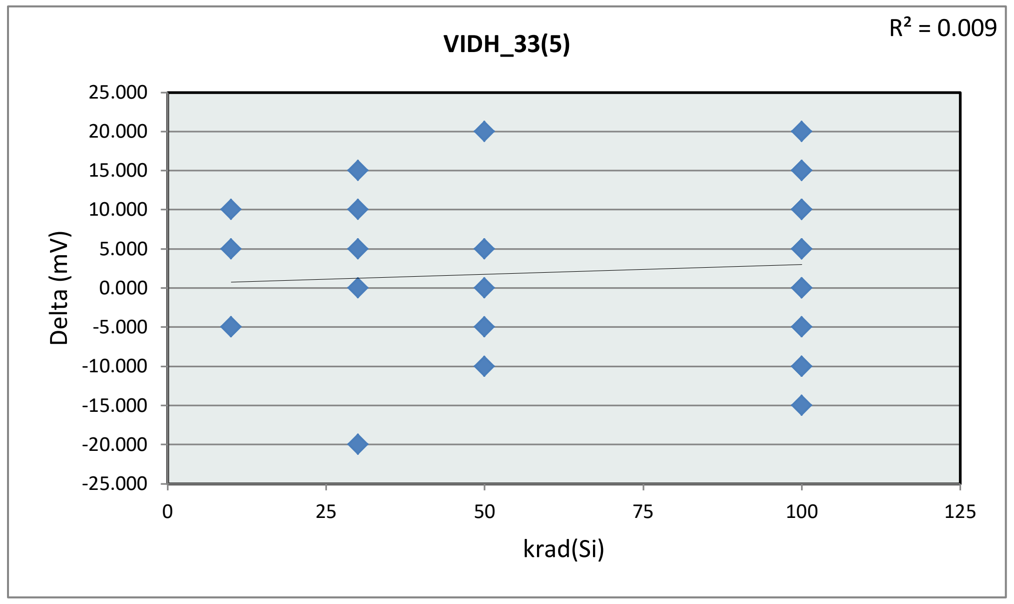


	DVTH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	25.000	25.000	25.000
Average	16.000	36.000	31.000	31.818
Max	25.000	50.000	35.000	50.000
UL	150.000	150.000	150.000	150.000

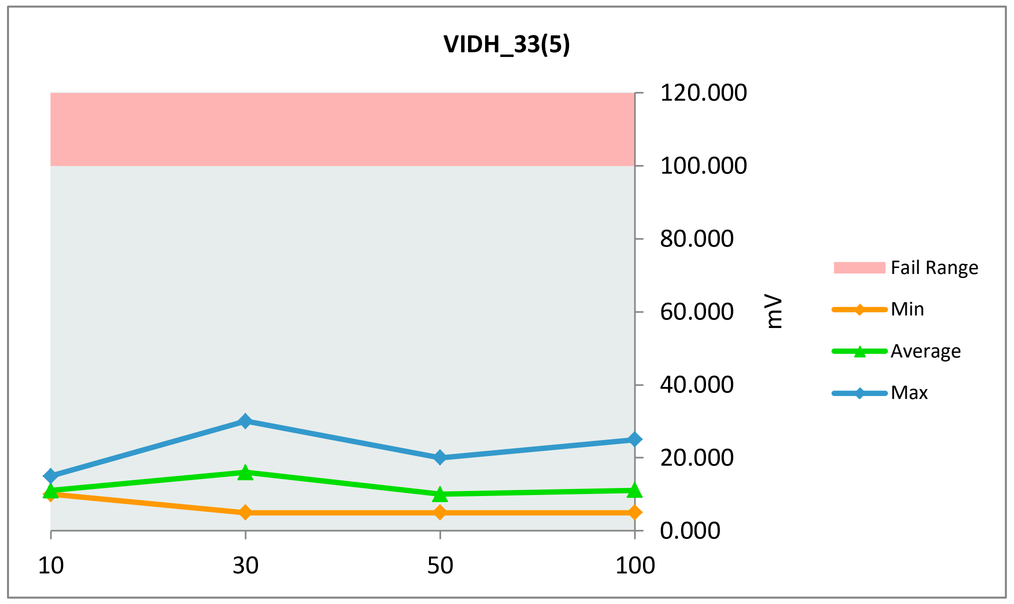


TID Report
SN55LVCP22A-SP

	VIDH_33(5)			
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	25.000	15.000	10.000
10	7	5.000	10.000	-5.000
10	8	5.000	10.000	-5.000
10	9	5.000	10.000	-5.000
10	10	15.000	10.000	5.000
30	6	10.000	5.000	5.000
30	7	30.000	30.000	0.000
30	8	20.000	5.000	15.000
30	9	25.000	15.000	10.000
30	10	5.000	25.000	-20.000
50	16	15.000	20.000	-5.000
50	17	5.000	5.000	0.000
50	18	5.000	15.000	-10.000
50	19	25.000	5.000	20.000
50	20	10.000	5.000	5.000
100	B043	20.000	5.000	15.000
100	B044	20.000	5.000	15.000
100	B045	5.000	5.000	0.000
100	B046	15.000	20.000	-5.000
100	B047	5.000	20.000	-15.000
100	B048	5.000	5.000	0.000
100	B049	15.000	5.000	10.000
100	B050	5.000	15.000	-10.000
100	B051	20.000	5.000	15.000
100	B052	15.000	5.000	10.000
100	B053	15.000	5.000	10.000
100	B054	25.000	5.000	20.000
100	B055	5.000	5.000	0.000
100	B056	20.000	15.000	5.000
100	B057	5.000	15.000	-10.000
100	B058	25.000	25.000	0.000
100	B059	10.000	5.000	5.000
100	B060	25.000	20.000	5.000
100	B061	5.000	5.000	0.000
100	B062	15.000	25.000	-10.000
100	B063	15.000	5.000	10.000
100	B064	20.000	25.000	-5.000
	Max	30.000	30.000	20.000
	Average	13.919	11.622	2.297
	Min	5.000	5.000	-20.000
	Std Dev	8.005	7.822	9.761

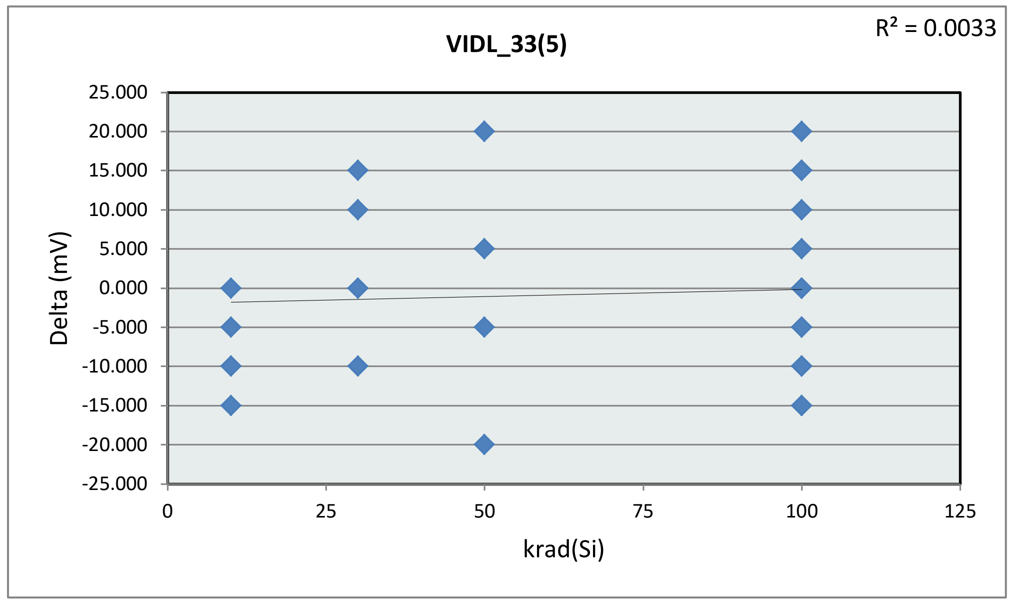


	VIDH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	11.000	16.000	10.000	11.136
Max	15.000	30.000	20.000	25.000
UL	100.000	100.000	100.000	100.000

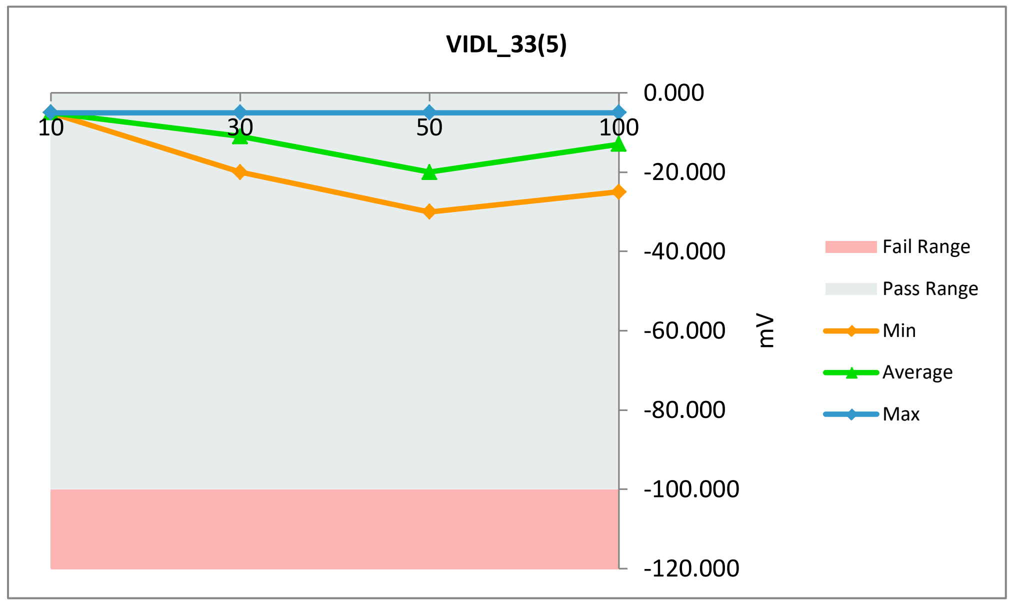


TID Report
SN55LVCP22A-SP

		VIDL_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-20.000	-5.000	-15.000
10	8	-10.000	-5.000	-5.000
10	9	-15.000	-5.000	-10.000
10	10	-5.000	-5.000	0.000
30	6	-10.000	-10.000	0.000
30	7	-5.000	-5.000	0.000
30	8	-5.000	-20.000	15.000
30	9	-5.000	-15.000	10.000
30	10	-15.000	-5.000	-10.000
50	16	-10.000	-5.000	-5.000
50	17	-25.000	-30.000	5.000
50	18	-30.000	-10.000	-20.000
50	19	-5.000	-25.000	20.000
50	20	-10.000	-30.000	20.000
100	B043	-25.000	-20.000	-5.000
100	B044	-5.000	-25.000	20.000
100	B045	-10.000	-5.000	-5.000
100	B046	-15.000	-25.000	10.000
100	B047	-20.000	-5.000	-15.000
100	B048	-15.000	-10.000	-5.000
100	B049	-15.000	-20.000	5.000
100	B050	-25.000	-15.000	-10.000
100	B051	-5.000	-20.000	15.000
100	B052	-5.000	-5.000	0.000
100	B053	-15.000	-15.000	0.000
100	B054	-20.000	-20.000	0.000
100	B055	-15.000	-5.000	-10.000
100	B056	-5.000	-5.000	0.000
100	B057	-20.000	-5.000	-15.000
100	B058	-5.000	-20.000	15.000
100	B059	-20.000	-5.000	-15.000
100	B060	-5.000	-5.000	0.000
100	B061	-30.000	-20.000	-10.000
100	B062	-15.000	-5.000	-10.000
100	B063	-5.000	-20.000	15.000
100	B064	-10.000	-10.000	0.000
	Max	-5.000	-5.000	20.000
	Average	-13.243	-12.568	-0.676
	Min	-30.000	-30.000	-20.000
	Std Dev	7.657	8.385	11.128

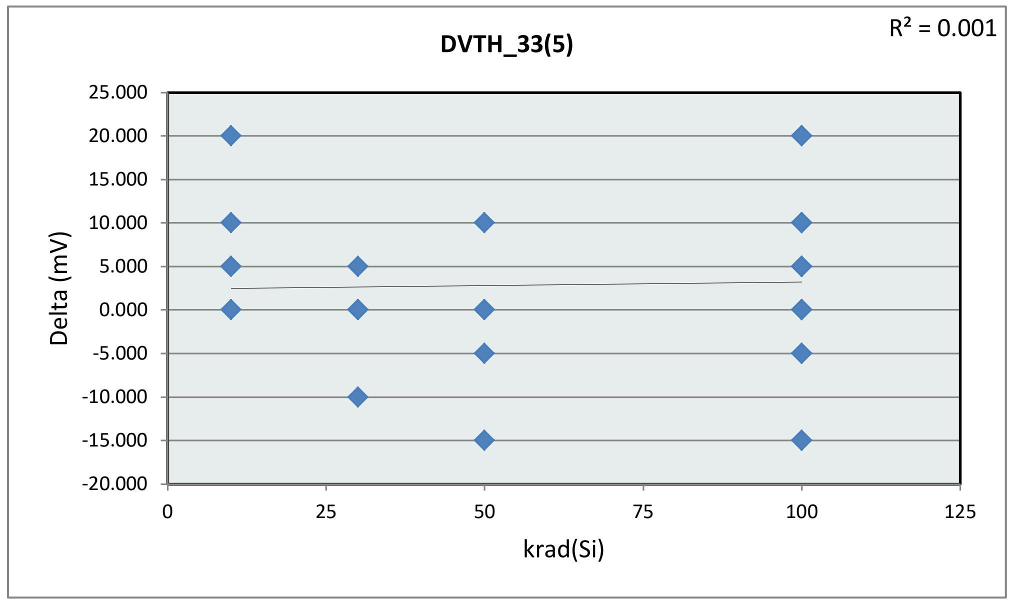


	VIDL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-20.000	-30.000	-25.000
Average	-5.000	-11.000	-20.000	-12.955
Max	-5.000	-5.000	-5.000	-5.000
UL				

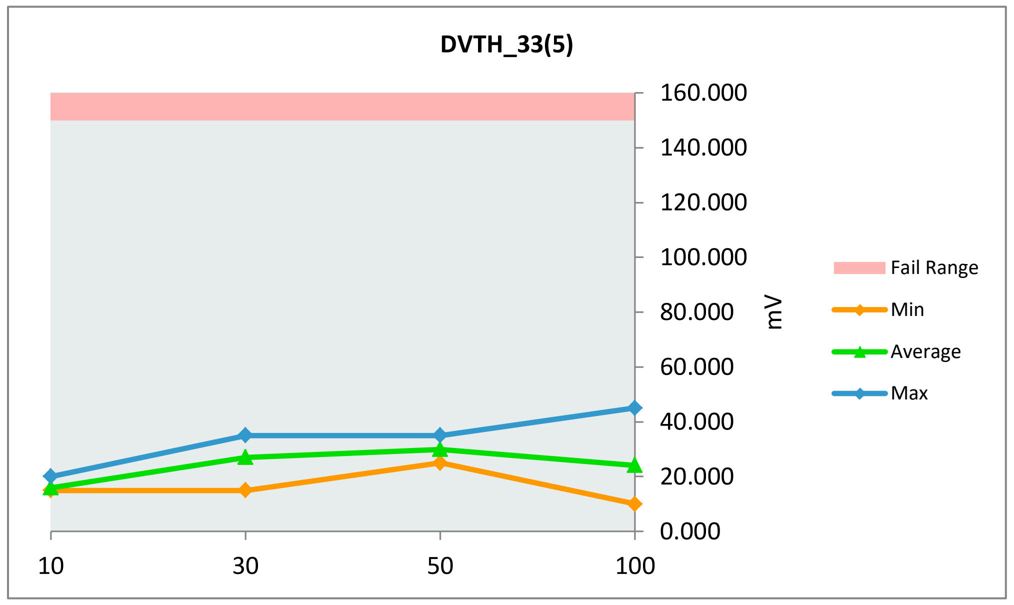


TID Report
SN55LVCP22A-SP

		DVTH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	40.000	20.000	20.000
10	7	25.000	15.000	10.000
10	8	15.000	15.000	0.000
10	9	20.000	15.000	5.000
10	10	20.000	15.000	5.000
30	6	20.000	15.000	5.000
30	7	35.000	35.000	0.000
30	8	25.000	25.000	0.000
30	9	30.000	30.000	0.000
30	10	20.000	30.000	-10.000
50	16	25.000	25.000	0.000
50	17	30.000	35.000	-5.000
50	18	35.000	25.000	10.000
50	19	30.000	30.000	0.000
50	20	20.000	35.000	-15.000
100	B043	45.000	25.000	20.000
100	B044	25.000	30.000	-5.000
100	B045	15.000	10.000	5.000
100	B046	30.000	45.000	-15.000
100	B047	25.000	25.000	0.000
100	B048	20.000	15.000	5.000
100	B049	30.000	25.000	5.000
100	B050	30.000	30.000	0.000
100	B051	25.000	25.000	0.000
100	B052	20.000	10.000	10.000
100	B053	30.000	20.000	10.000
100	B054	45.000	25.000	20.000
100	B055	20.000	10.000	10.000
100	B056	25.000	20.000	5.000
100	B057	25.000	20.000	5.000
100	B058	30.000	45.000	-15.000
100	B059	30.000	10.000	20.000
100	B060	30.000	25.000	5.000
100	B061	35.000	25.000	10.000
100	B062	30.000	30.000	0.000
100	B063	20.000	25.000	-5.000
100	B064	30.000	35.000	-5.000
	Max	45.000	45.000	20.000
	Average	27.162	24.189	2.973
	Min	15.000	10.000	-15.000
	Std Dev	7.221	9.015	9.087

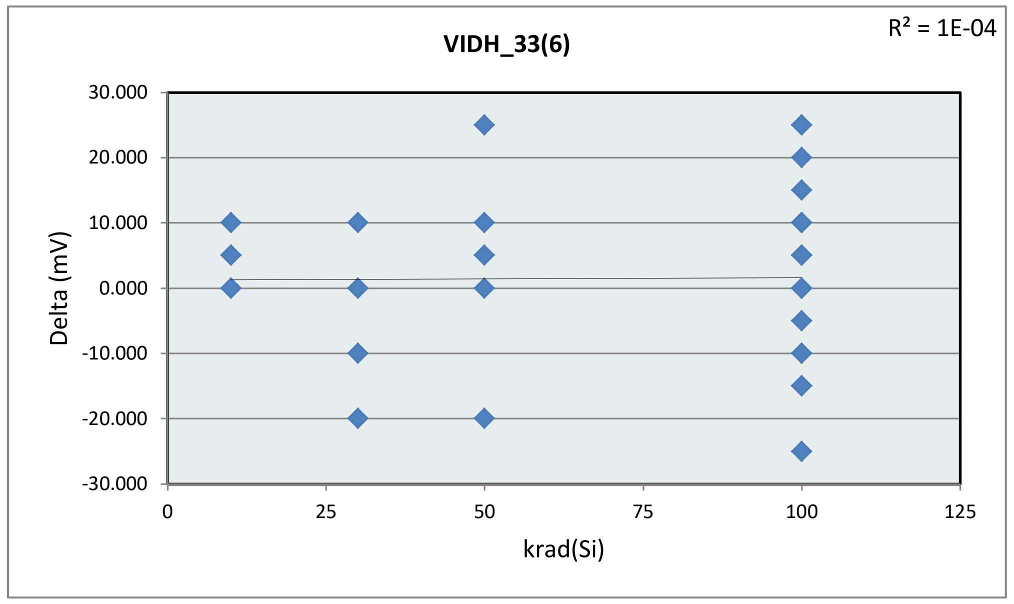


	DVTH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	15.000	25.000	10.000
Average	16.000	27.000	30.000	24.091
Max	20.000	35.000	35.000	45.000
UL	150.000	150.000	150.000	150.000

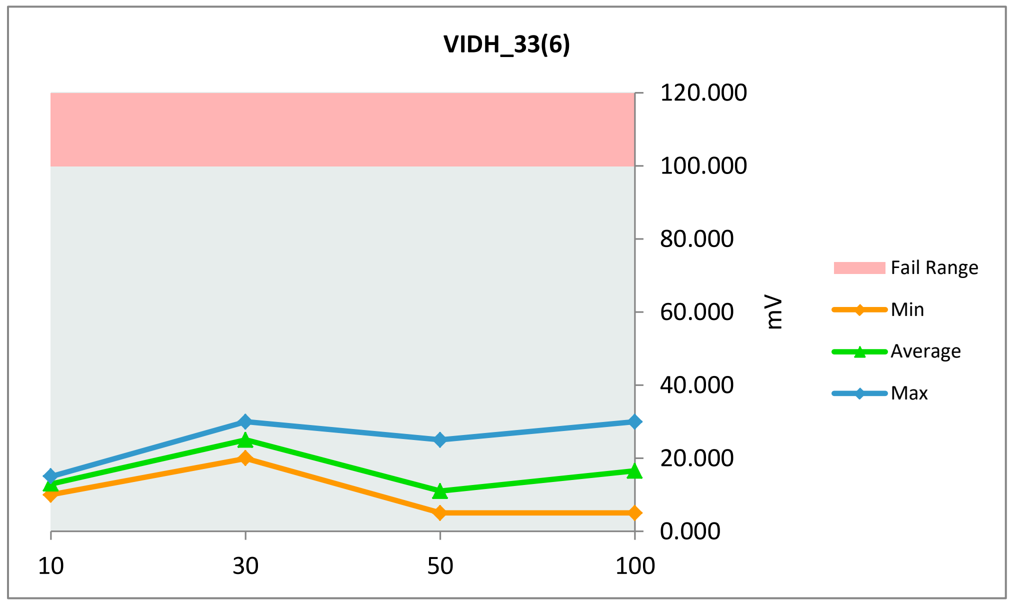


TID Report
SN55LVCP22A-SP

		VIDH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	20.000	15.000	5.000
10	7	15.000	15.000	0.000
10	8	15.000	15.000	0.000
10	9	20.000	10.000	10.000
10	10	15.000	10.000	5.000
30	6	20.000	20.000	0.000
30	7	30.000	30.000	0.000
30	8	30.000	20.000	10.000
30	9	20.000	30.000	-10.000
30	10	5.000	25.000	-20.000
50	16	25.000	15.000	10.000
50	17	10.000	5.000	5.000
50	18	5.000	25.000	-20.000
50	19	30.000	5.000	25.000
50	20	5.000	5.000	0.000
100	B043	30.000	5.000	25.000
100	B044	20.000	5.000	15.000
100	B045	5.000	20.000	-15.000
100	B046	5.000	30.000	-25.000
100	B047	5.000	15.000	-10.000
100	B048	15.000	5.000	10.000
100	B049	25.000	15.000	10.000
100	B050	5.000	5.000	0.000
100	B051	25.000	5.000	20.000
100	B052	20.000	10.000	10.000
100	B053	5.000	20.000	-15.000
100	B054	30.000	5.000	25.000
100	B055	25.000	25.000	0.000
100	B056	25.000	20.000	5.000
100	B057	15.000	10.000	5.000
100	B058	20.000	30.000	-10.000
100	B059	25.000	25.000	0.000
100	B060	30.000	25.000	5.000
100	B061	15.000	15.000	0.000
100	B062	5.000	20.000	-15.000
100	B063	20.000	25.000	-5.000
100	B064	30.000	30.000	0.000
	Max	30.000	30.000	25.000
	Average	17.973	16.486	1.486
	Min	5.000	5.000	-25.000
	Std Dev	9.087	8.809	12.465

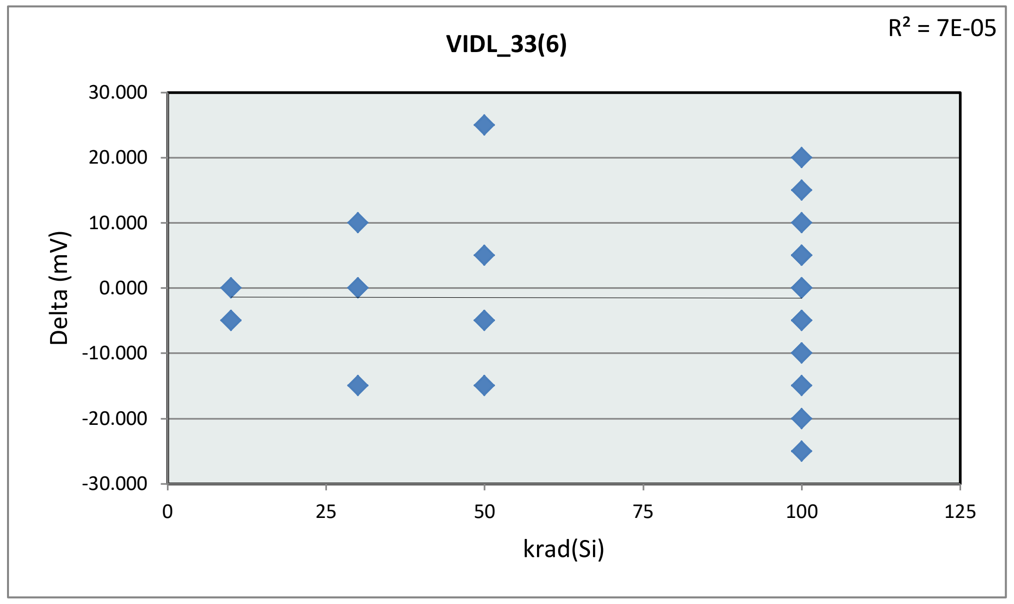


	VIDH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	5.000	5.000
Average	13.000	25.000	11.000	16.591
Max	15.000	30.000	25.000	30.000
UL	100.000	100.000	100.000	100.000

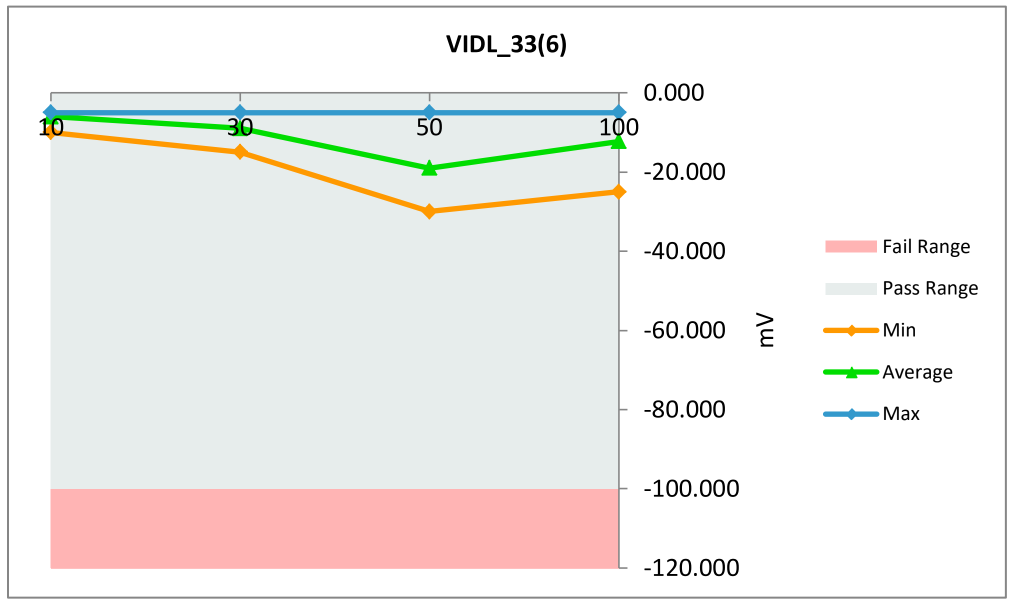


TID Report
SN55LVCP22A-SP

		VIDL_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-10.000	-5.000	-5.000
10	8	-10.000	-5.000	-5.000
10	9	-5.000	-5.000	0.000
10	10	-10.000	-10.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-15.000	-15.000	0.000
30	8	-5.000	-15.000	10.000
30	9	-5.000	-5.000	0.000
30	10	-20.000	-5.000	-15.000
50	16	-5.000	-10.000	5.000
50	17	-35.000	-30.000	-5.000
50	18	-20.000	-5.000	-15.000
50	19	-5.000	-30.000	25.000
50	20	-25.000	-20.000	-5.000
100	B043	-20.000	-20.000	0.000
100	B044	-10.000	-20.000	10.000
100	B045	-25.000	-5.000	-20.000
100	B046	-20.000	-15.000	-5.000
100	B047	-30.000	-5.000	-25.000
100	B048	-15.000	-20.000	5.000
100	B049	-5.000	-20.000	15.000
100	B050	-25.000	-20.000	-5.000
100	B051	-5.000	-25.000	20.000
100	B052	-5.000	-10.000	5.000
100	B053	-20.000	-5.000	-15.000
100	B054	-20.000	-20.000	0.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-15.000	-20.000	5.000
100	B058	-10.000	-15.000	5.000
100	B059	-10.000	-5.000	-5.000
100	B060	-5.000	-5.000	0.000
100	B061	-20.000	-10.000	-10.000
100	B062	-20.000	-10.000	-10.000
100	B063	-15.000	-5.000	-10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-13.378	-11.892	-1.486
	Min	-35.000	-30.000	-25.000
	Std Dev	8.338	7.849	10.129



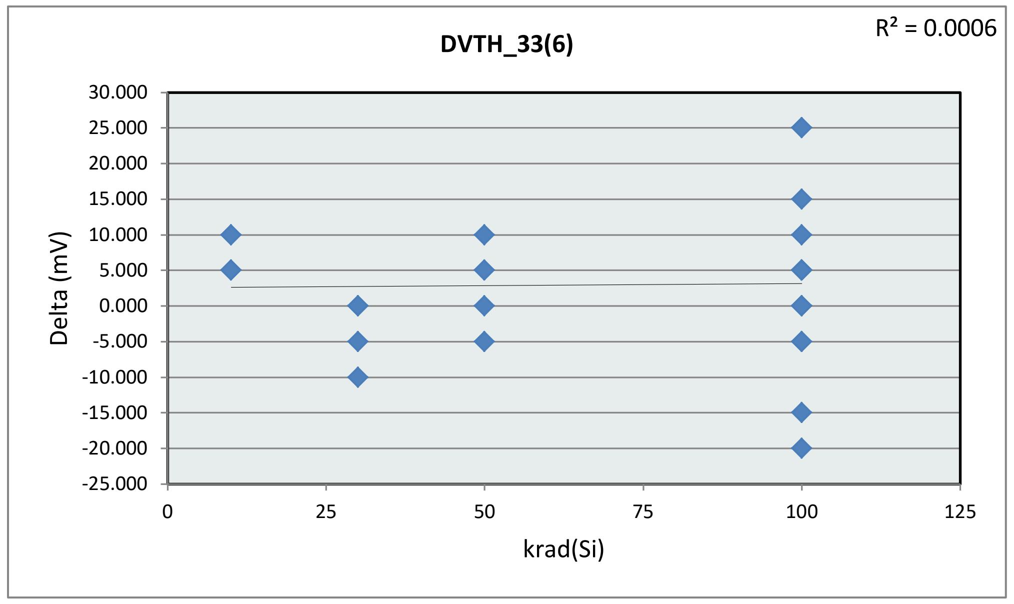
	VIDL_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-10.000	-15.000	-30.000	-25.000
Average	-6.000	-9.000	-19.000	-12.273
Max	-5.000	-5.000	-5.000	-5.000
UL				



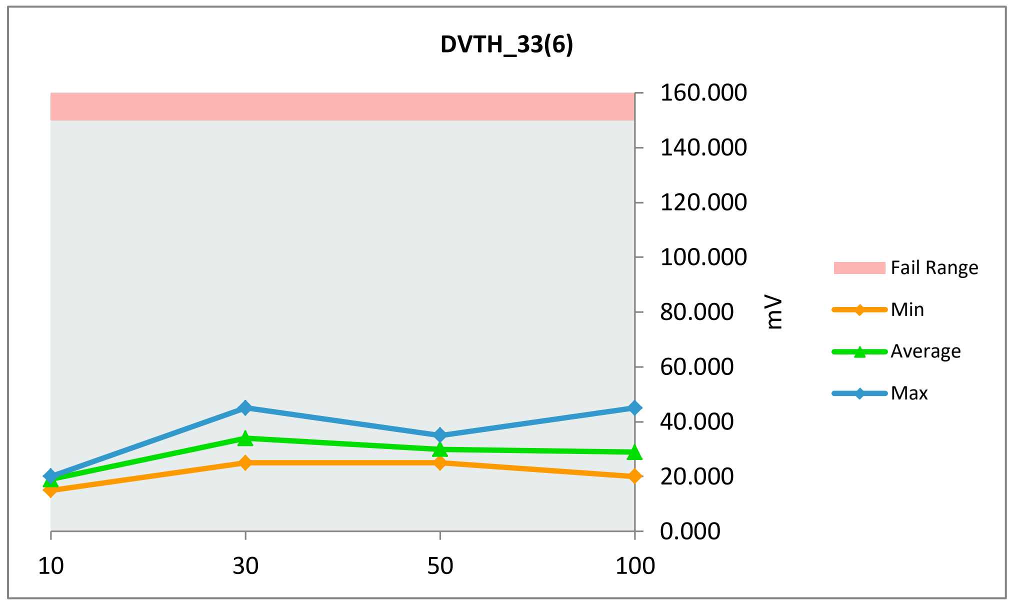
TID Report
SN55LVCP22A-SP

	DVTH_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	30.000	20.000	10.000
10	7	25.000	20.000	5.000
10	8	25.000	20.000	5.000
10	9	25.000	15.000	10.000
10	10	25.000	20.000	5.000
30	6	25.000	25.000	0.000
30	7	45.000	45.000	0.000
30	8	35.000	35.000	0.000
30	9	25.000	35.000	-10.000
30	10	25.000	30.000	-5.000
50	16	30.000	25.000	5.000
50	17	45.000	35.000	10.000
50	18	25.000	30.000	-5.000
50	19	35.000	35.000	0.000
50	20	30.000	25.000	5.000
100	B043	50.000	25.000	25.000
100	B044	30.000	25.000	5.000
100	B045	30.000	25.000	5.000
100	B046	25.000	45.000	-20.000
100	B047	35.000	20.000	15.000
100	B048	30.000	25.000	5.000
100	B049	30.000	35.000	-5.000
100	B050	30.000	25.000	5.000
100	B051	30.000	30.000	0.000
100	B052	25.000	20.000	5.000
100	B053	25.000	25.000	0.000
100	B054	50.000	25.000	25.000
100	B055	30.000	30.000	0.000
100	B056	30.000	25.000	5.000
100	B057	30.000	30.000	0.000
100	B058	30.000	45.000	-15.000
100	B059	35.000	30.000	5.000
100	B060	35.000	30.000	5.000
100	B061	35.000	25.000	10.000
100	B062	25.000	30.000	-5.000
100	B063	35.000	30.000	5.000
100	B064	35.000	35.000	0.000
	Max	50.000	45.000	25.000
	Average	31.351	28.378	2.973
	Min	25.000	15.000	-20.000
	Std Dev	6.836	7.174	8.697

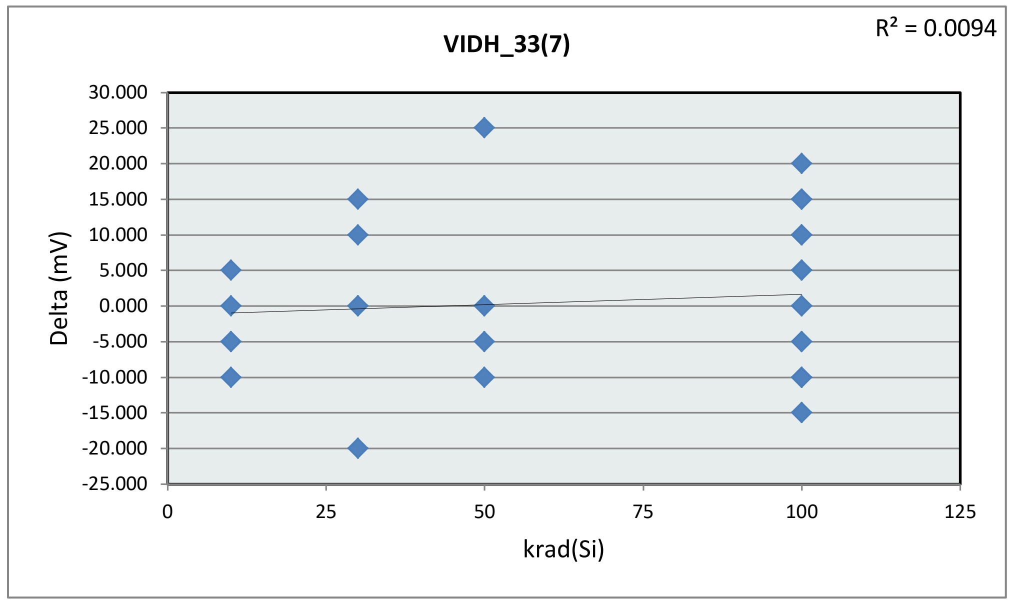


	DVTH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	25.000	20.000
Average	19.000	34.000	30.000	28.864
Max	20.000	45.000	35.000	45.000
UL	150.000	150.000	150.000	150.000

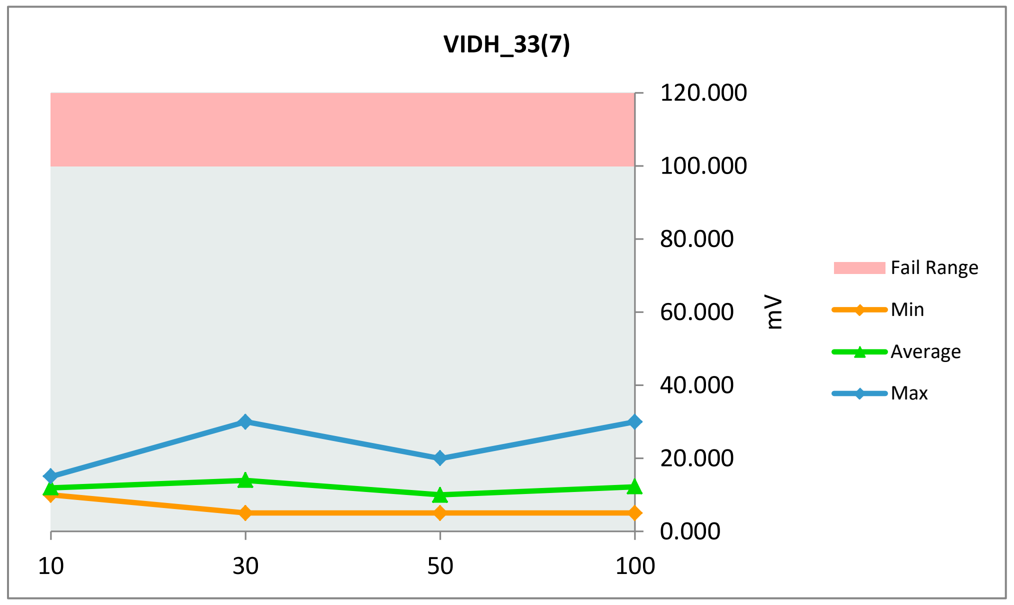


TID Report
SN55LVCP22A-SP

		VIDH_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	20.000	15.000	5.000
10	7	5.000	10.000	-5.000
10	8	10.000	10.000	0.000
10	9	5.000	15.000	-10.000
10	10	5.000	10.000	-5.000
30	6	5.000	5.000	0.000
30	7	30.000	30.000	0.000
30	8	15.000	5.000	10.000
30	9	20.000	5.000	15.000
30	10	5.000	25.000	-20.000
50	16	15.000	20.000	-5.000
50	17	5.000	5.000	0.000
50	18	5.000	15.000	-10.000
50	19	30.000	5.000	25.000
50	20	5.000	5.000	0.000
100	B043	20.000	5.000	15.000
100	B044	20.000	5.000	15.000
100	B045	5.000	15.000	-10.000
100	B046	15.000	20.000	-5.000
100	B047	5.000	20.000	-15.000
100	B048	5.000	10.000	-5.000
100	B049	5.000	15.000	-10.000
100	B050	5.000	15.000	-10.000
100	B051	20.000	5.000	15.000
100	B052	15.000	5.000	10.000
100	B053	15.000	5.000	10.000
100	B054	25.000	5.000	20.000
100	B055	5.000	15.000	-10.000
100	B056	20.000	15.000	5.000
100	B057	5.000	5.000	0.000
100	B058	25.000	25.000	0.000
100	B059	10.000	5.000	5.000
100	B060	25.000	15.000	10.000
100	B061	5.000	5.000	0.000
100	B062	15.000	30.000	-15.000
100	B063	15.000	5.000	10.000
100	B064	20.000	25.000	-5.000
	Max	30.000	30.000	25.000
	Average	12.973	12.162	0.811
	Min	5.000	5.000	-20.000
	Std Dev	8.204	7.865	10.640

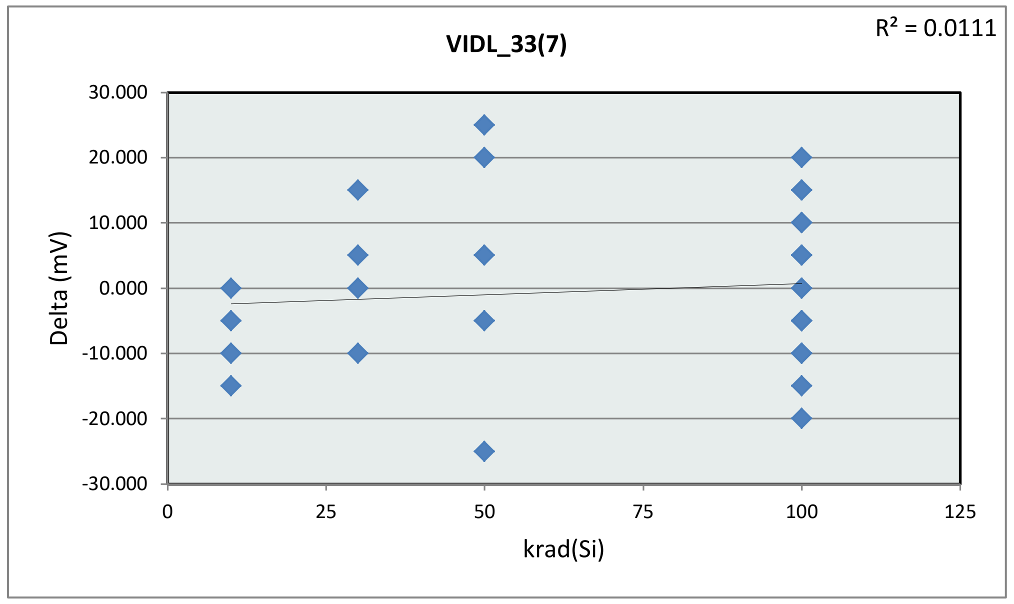


	VIDH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	12.000	14.000	10.000	12.273
Max	15.000	30.000	20.000	30.000
UL	100.000	100.000	100.000	100.000

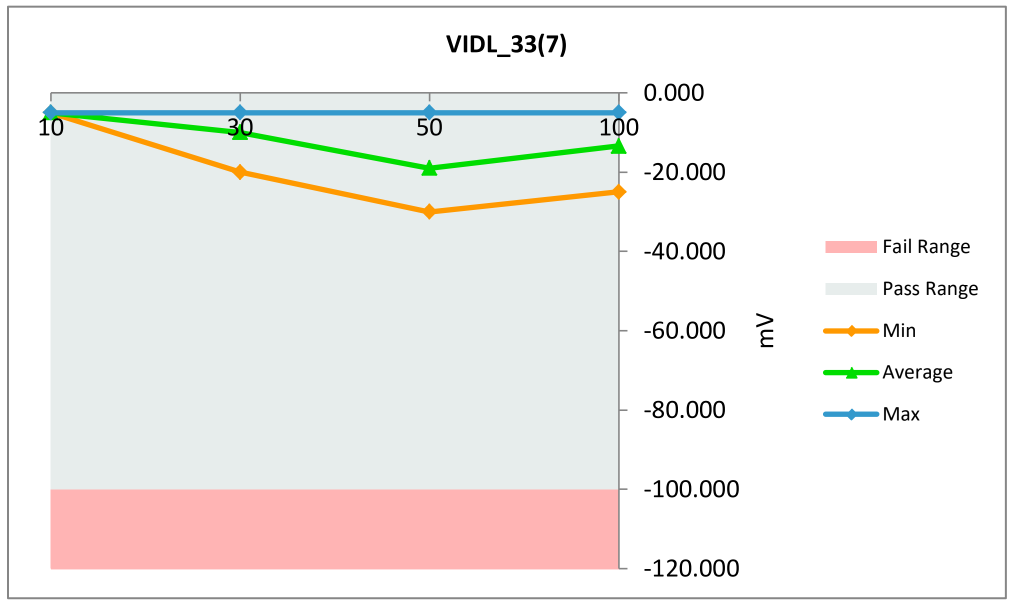


TID Report
SN55LVCP22A-SP

		VIDL_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-20.000	-5.000	-15.000
10	8	-15.000	-5.000	-10.000
10	9	-10.000	-5.000	-5.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-10.000	-10.000	0.000
30	8	-5.000	-20.000	15.000
30	9	-5.000	-10.000	5.000
30	10	-15.000	-5.000	-10.000
50	16	-10.000	-5.000	-5.000
50	17	-25.000	-30.000	5.000
50	18	-30.000	-5.000	-25.000
50	19	-5.000	-25.000	20.000
50	20	-5.000	-30.000	25.000
100	B043	-25.000	-20.000	-5.000
100	B044	-5.000	-25.000	20.000
100	B045	-10.000	-5.000	-5.000
100	B046	-15.000	-25.000	10.000
100	B047	-25.000	-5.000	-20.000
100	B048	-15.000	-10.000	-5.000
100	B049	-15.000	-20.000	5.000
100	B050	-25.000	-15.000	-10.000
100	B051	-5.000	-20.000	15.000
100	B052	-5.000	-15.000	10.000
100	B053	-5.000	-15.000	10.000
100	B054	-20.000	-25.000	5.000
100	B055	-10.000	-5.000	-5.000
100	B056	-5.000	-5.000	0.000
100	B057	-20.000	-5.000	-15.000
100	B058	-5.000	-20.000	15.000
100	B059	-20.000	-10.000	-10.000
100	B060	-10.000	-5.000	-5.000
100	B061	-30.000	-20.000	-10.000
100	B062	-15.000	-5.000	-10.000
100	B063	-5.000	-15.000	10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-12.838	-12.568	-0.270
	Min	-30.000	-30.000	-25.000
	Std Dev	8.040	8.467	11.723



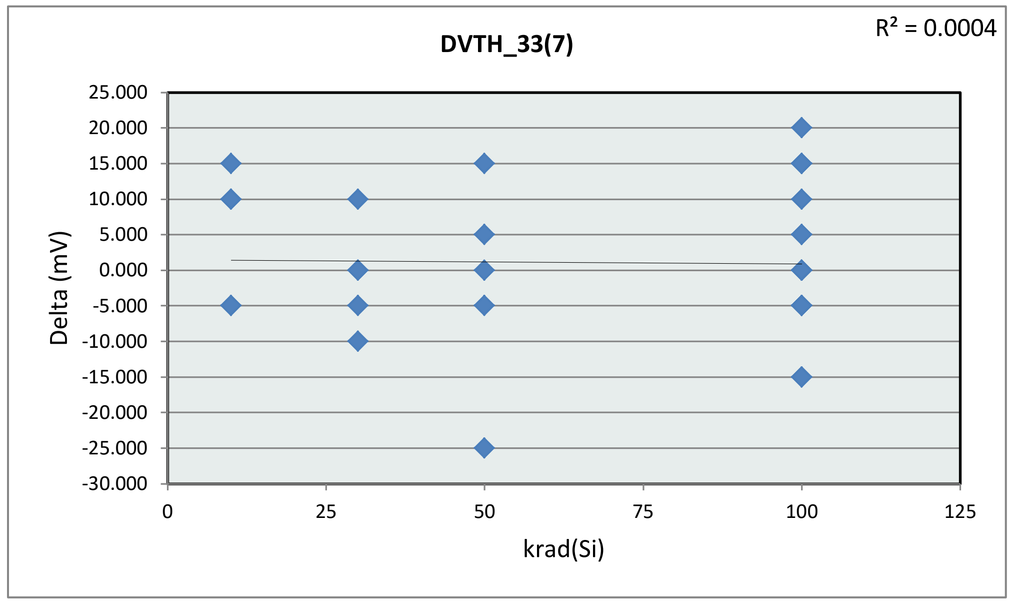
	VIDL_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-20.000	-30.000	-25.000
Average	-5.000	-10.000	-19.000	-13.409
Max	-5.000	-5.000	-5.000	-5.000
UL				



TID Report
SN55LVCP22A-SP

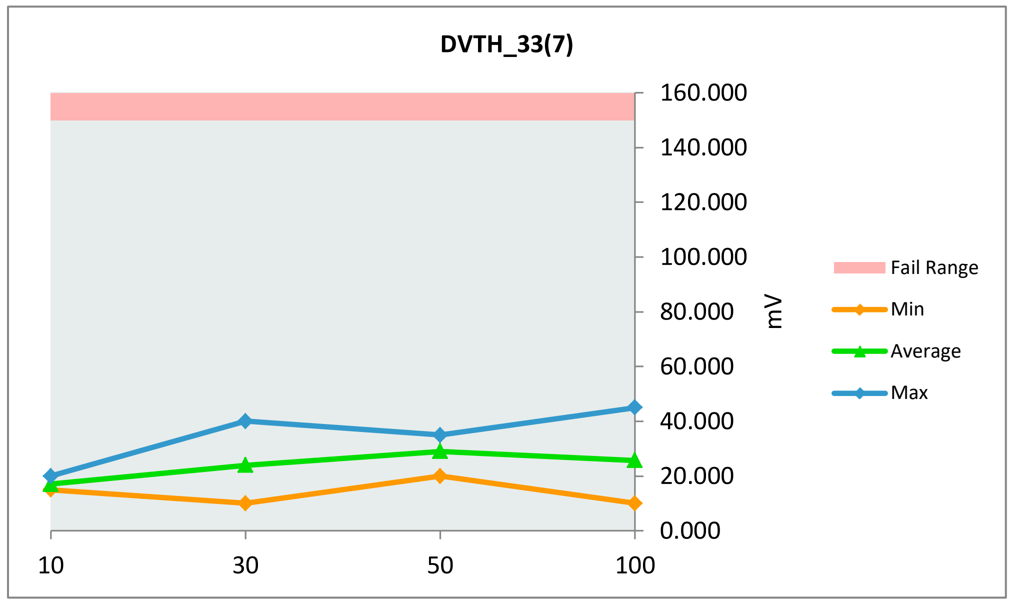
	DVTH_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	35.000	20.000	15.000
10	7	25.000	15.000	10.000
10	8	25.000	15.000	10.000
10	9	15.000	20.000	-5.000
10	10	10.000	15.000	-5.000
30	6	10.000	10.000	0.000
30	7	40.000	40.000	0.000
30	8	20.000	25.000	-5.000
30	9	25.000	15.000	10.000
30	10	20.000	30.000	-10.000
50	16	25.000	25.000	0.000
50	17	30.000	35.000	-5.000
50	18	35.000	20.000	15.000
50	19	35.000	30.000	5.000
50	20	10.000	35.000	-25.000
100	B043	45.000	25.000	20.000
100	B044	25.000	30.000	-5.000
100	B045	15.000	20.000	-5.000
100	B046	30.000	45.000	-15.000
100	B047	30.000	25.000	5.000
100	B048	20.000	20.000	0.000
100	B049	20.000	35.000	-15.000
100	B050	30.000	30.000	0.000
100	B051	25.000	25.000	0.000
100	B052	20.000	20.000	0.000
100	B053	20.000	20.000	0.000
100	B054	45.000	30.000	15.000
100	B055	15.000	20.000	-5.000
100	B056	25.000	20.000	5.000
100	B057	25.000	10.000	15.000
100	B058	30.000	45.000	-15.000
100	B059	30.000	15.000	15.000
100	B060	35.000	20.000	15.000
100	B061	35.000	25.000	10.000
100	B062	30.000	35.000	-5.000
100	B063	20.000	20.000	0.000
100	B064	25.000	30.000	-5.000
	Max	45.000	45.000	20.000
	Average	25.811	24.730	1.081
	Min	10.000	10.000	-25.000
	Std Dev	8.860	8.815	10.283



	DVTH_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	mV
Min Limit		mV

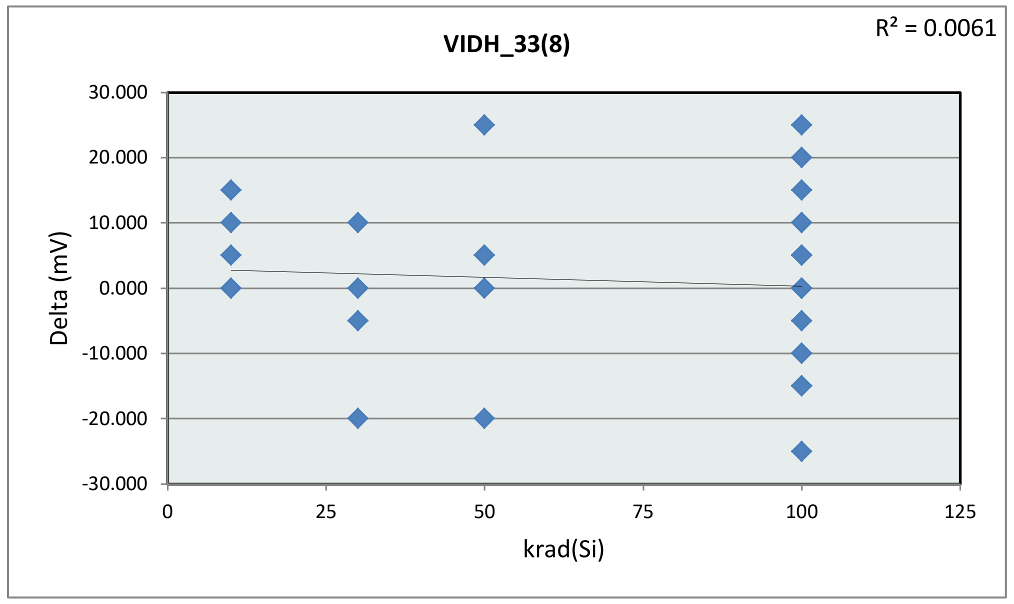
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	20.000	10.000
Average	17.000	24.000	29.000	25.682
Max	20.000	40.000	35.000	45.000
UL	150.000	150.000	150.000	150.000



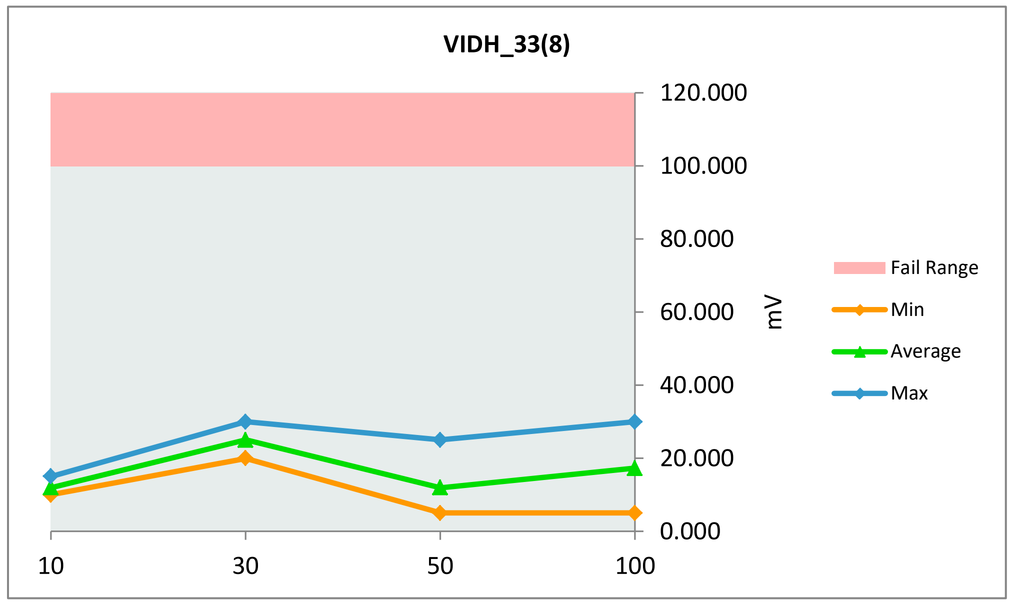
TID Report
SN55LVCP22A-SP

	VIDH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	20.000	10.000	10.000
10	7	15.000	10.000	5.000
10	8	15.000	15.000	0.000
10	9	25.000	10.000	15.000
10	10	15.000	15.000	0.000
30	6	20.000	20.000	0.000
30	7	30.000	30.000	0.000
30	8	30.000	20.000	10.000
30	9	25.000	30.000	-5.000
30	10	5.000	25.000	-20.000
50	16	25.000	20.000	5.000
50	17	10.000	5.000	5.000
50	18	5.000	25.000	-20.000
50	19	30.000	5.000	25.000
50	20	5.000	5.000	0.000
100	B043	25.000	5.000	20.000
100	B044	20.000	5.000	15.000
100	B045	5.000	20.000	-15.000
100	B046	5.000	30.000	-25.000
100	B047	5.000	15.000	-10.000
100	B048	10.000	5.000	5.000
100	B049	25.000	15.000	10.000
100	B050	5.000	15.000	-10.000
100	B051	25.000	5.000	20.000
100	B052	20.000	10.000	10.000
100	B053	10.000	25.000	-15.000
100	B054	30.000	5.000	25.000
100	B055	25.000	25.000	0.000
100	B056	25.000	20.000	5.000
100	B057	10.000	10.000	0.000
100	B058	20.000	30.000	-10.000
100	B059	25.000	25.000	0.000
100	B060	30.000	25.000	5.000
100	B061	15.000	15.000	0.000
100	B062	5.000	20.000	-15.000
100	B063	20.000	25.000	-5.000
100	B064	30.000	30.000	0.000
	Max	30.000	30.000	25.000
	Average	17.973	16.892	1.081
	Min	5.000	5.000	-25.000
	Std Dev	9.087	8.768	12.312

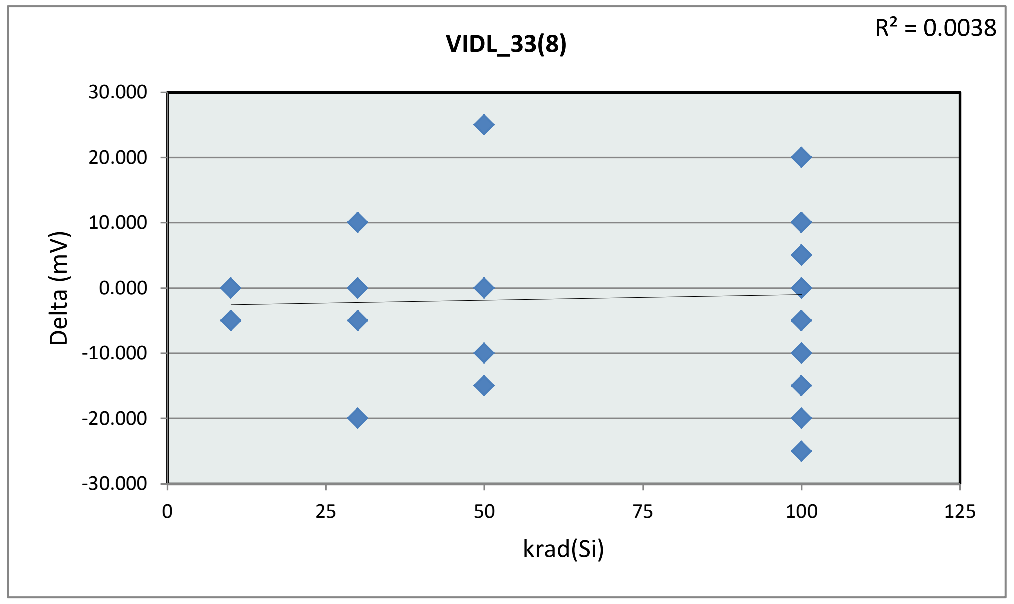


	VIDH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	5.000	5.000
Average	12.000	25.000	12.000	17.273
Max	15.000	30.000	25.000	30.000
UL	100.000	100.000	100.000	100.000

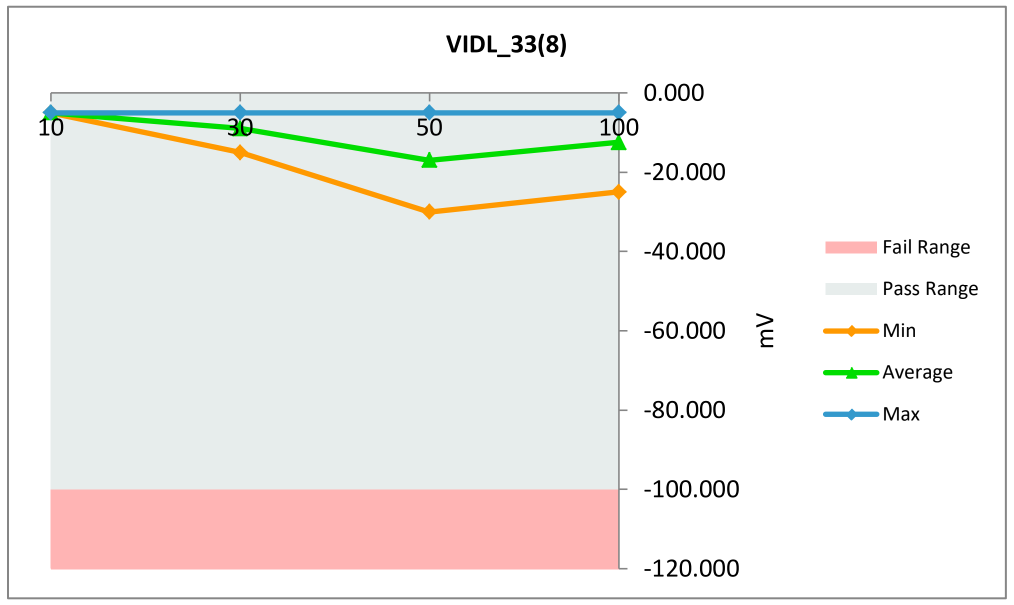


TID Report
SN55LVCP22A-SP

		VIDL_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-10.000	-5.000	-5.000
10	8	-10.000	-5.000	-5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-15.000	-15.000	0.000
30	8	-5.000	-15.000	10.000
30	9	-10.000	-5.000	-5.000
30	10	-25.000	-5.000	-20.000
50	16	-5.000	-5.000	0.000
50	17	-30.000	-30.000	0.000
50	18	-20.000	-5.000	-15.000
50	19	-5.000	-30.000	25.000
50	20	-25.000	-15.000	-10.000
100	B043	-20.000	-25.000	5.000
100	B044	-10.000	-20.000	10.000
100	B045	-25.000	-5.000	-20.000
100	B046	-20.000	-15.000	-5.000
100	B047	-30.000	-5.000	-25.000
100	B048	-15.000	-20.000	5.000
100	B049	-10.000	-20.000	10.000
100	B050	-25.000	-20.000	-5.000
100	B051	-5.000	-25.000	20.000
100	B052	-5.000	-10.000	5.000
100	B053	-20.000	-5.000	-15.000
100	B054	-15.000	-20.000	5.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-10.000	-20.000	10.000
100	B058	-10.000	-15.000	5.000
100	B059	-10.000	-5.000	-5.000
100	B060	-5.000	-5.000	0.000
100	B061	-20.000	-10.000	-10.000
100	B062	-20.000	-10.000	-10.000
100	B063	-10.000	-5.000	-5.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-13.108	-11.622	-1.486
	Min	-30.000	-30.000	-25.000
	Std Dev	8.024	8.084	10.332

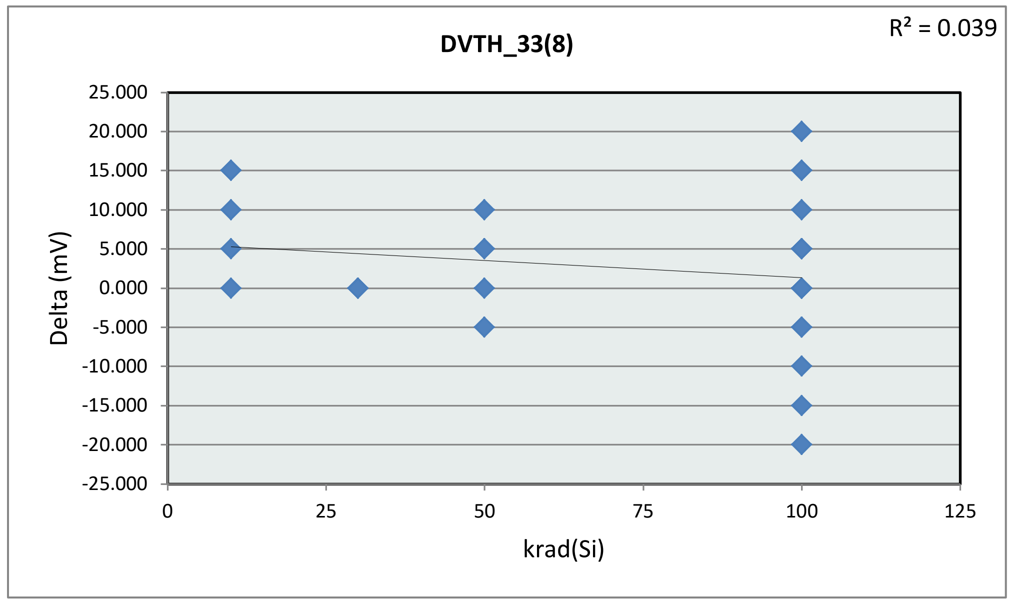


	VIDL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-15.000	-30.000	-25.000
Average	-5.000	-9.000	-17.000	-12.500
Max	-5.000	-5.000	-5.000	-5.000
UL				

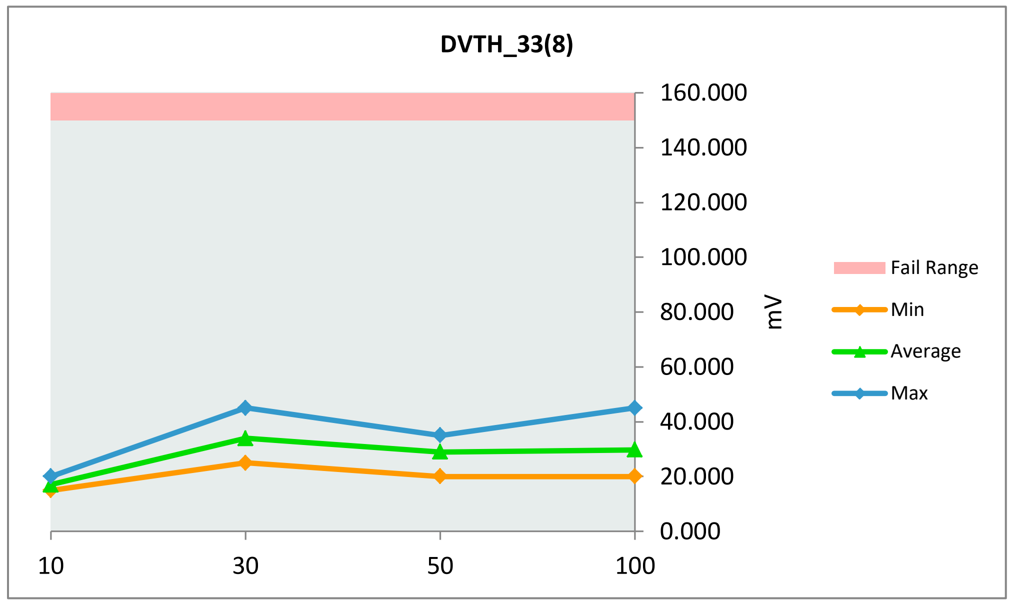


TID Report
SN55LVCP22A-SP

		DVTH_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	30.000	15.000	15.000
10	7	25.000	15.000	10.000
10	8	25.000	20.000	5.000
10	9	30.000	15.000	15.000
10	10	20.000	20.000	0.000
30	6	25.000	25.000	0.000
30	7	45.000	45.000	0.000
30	8	35.000	35.000	0.000
30	9	35.000	35.000	0.000
30	10	30.000	30.000	0.000
50	16	30.000	25.000	5.000
50	17	40.000	35.000	5.000
50	18	25.000	30.000	-5.000
50	19	35.000	35.000	0.000
50	20	30.000	20.000	10.000
100	B043	45.000	30.000	15.000
100	B044	30.000	25.000	5.000
100	B045	30.000	25.000	5.000
100	B046	25.000	45.000	-20.000
100	B047	35.000	20.000	15.000
100	B048	25.000	25.000	0.000
100	B049	35.000	35.000	0.000
100	B050	30.000	35.000	-5.000
100	B051	30.000	30.000	0.000
100	B052	25.000	20.000	5.000
100	B053	30.000	30.000	0.000
100	B054	45.000	25.000	20.000
100	B055	30.000	30.000	0.000
100	B056	30.000	25.000	5.000
100	B057	20.000	30.000	-10.000
100	B058	30.000	45.000	-15.000
100	B059	35.000	30.000	5.000
100	B060	35.000	30.000	5.000
100	B061	35.000	25.000	10.000
100	B062	25.000	30.000	-5.000
100	B063	30.000	30.000	0.000
100	B064	35.000	35.000	0.000
	Max	45.000	45.000	20.000
	Average	31.081	28.514	2.568
	Min	20.000	15.000	-20.000
	Std Dev	6.139	7.716	8.133



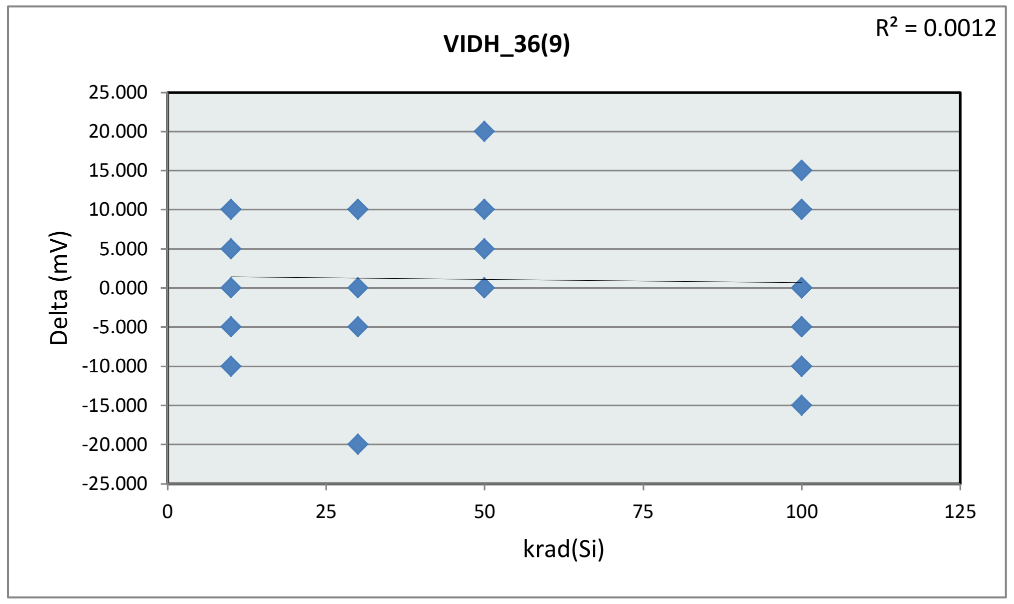
	DVTH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	25.000	20.000	20.000
Average	17.000	34.000	29.000	29.773
Max	20.000	45.000	35.000	45.000
UL	150.000	150.000	150.000	150.000



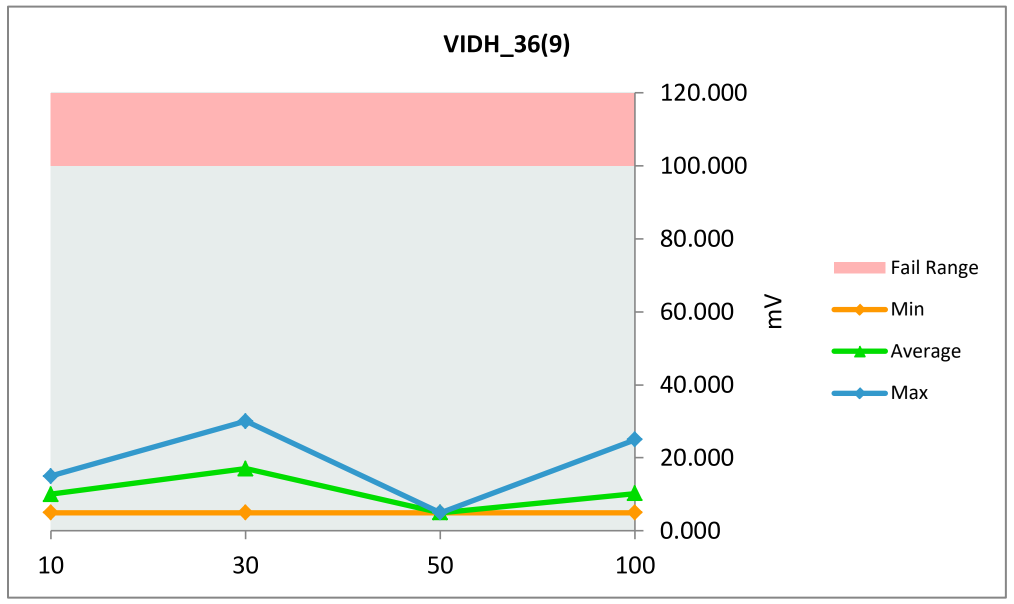
TID Report
SN55LVCP22A-SP

	VIDH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	20.000	10.000	10.000
10	7	5.000	5.000	0.000
10	8	5.000	10.000	-5.000
10	9	5.000	15.000	-10.000
10	10	15.000	10.000	5.000
30	6	5.000	10.000	-5.000
30	7	30.000	30.000	0.000
30	8	15.000	5.000	10.000
30	9	25.000	15.000	10.000
30	10	5.000	25.000	-20.000
50	16	15.000	5.000	10.000
50	17	5.000	5.000	0.000
50	18	5.000	5.000	0.000
50	19	25.000	5.000	20.000
50	20	10.000	5.000	5.000
100	B043	20.000	5.000	15.000
100	B044	20.000	5.000	15.000
100	B045	5.000	5.000	0.000
100	B046	5.000	5.000	0.000
100	B047	5.000	20.000	-15.000
100	B048	5.000	5.000	0.000
100	B049	5.000	15.000	-10.000
100	B050	5.000	15.000	-10.000
100	B051	15.000	5.000	10.000
100	B052	5.000	5.000	0.000
100	B053	5.000	5.000	0.000
100	B054	20.000	5.000	15.000
100	B055	5.000	5.000	0.000
100	B056	5.000	10.000	-5.000
100	B057	5.000	5.000	0.000
100	B058	20.000	20.000	0.000
100	B059	5.000	10.000	-5.000
100	B060	20.000	20.000	0.000
100	B061	5.000	5.000	0.000
100	B062	15.000	25.000	-10.000
100	B063	15.000	5.000	10.000
100	B064	20.000	25.000	-5.000
	Max	30.000	30.000	20.000
	Average	11.351	10.405	0.946
	Min	5.000	5.000	-20.000
	Std Dev	7.696	7.395	8.885

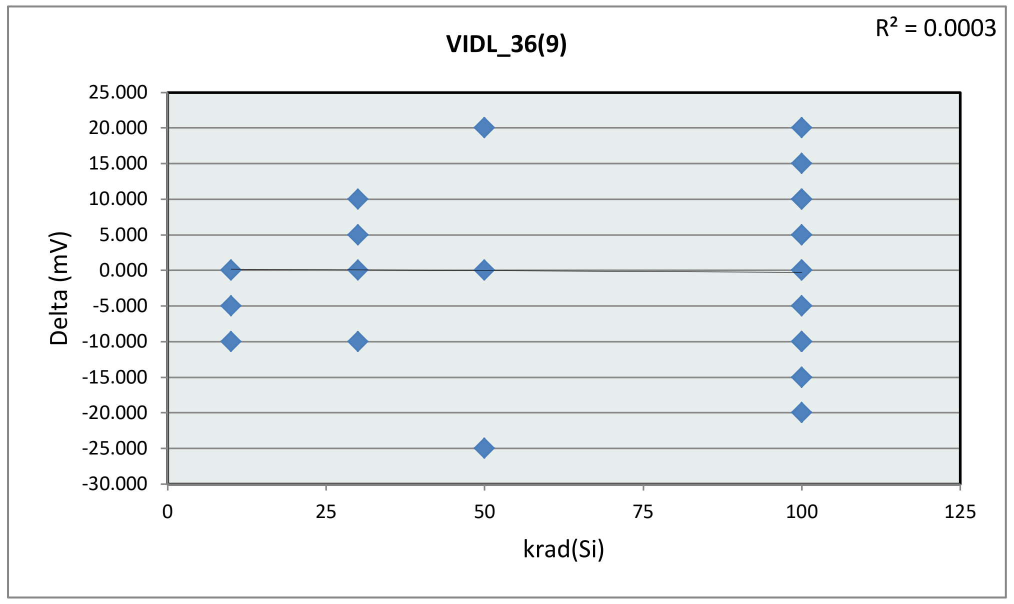


	VIDH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	10.000	17.000	5.000	10.227
Max	15.000	30.000	5.000	25.000
UL	100.000	100.000	100.000	100.000

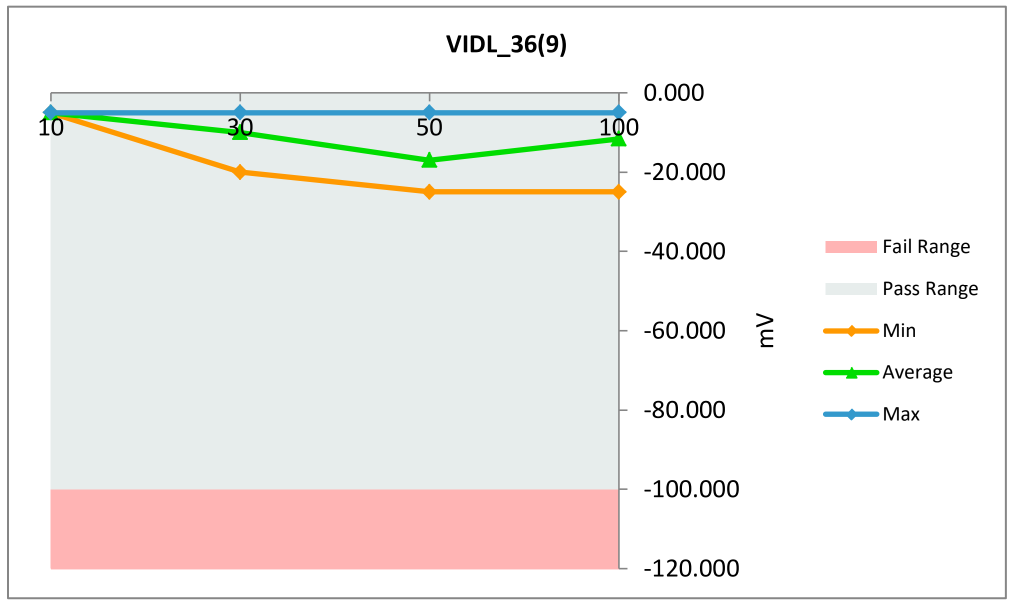


TID Report
SN55LVCP22A-SP

		VIDL_36(9)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-15.000	-5.000	-10.000
10	8	-5.000	-5.000	0.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-10.000	5.000
30	7	-5.000	-5.000	0.000
30	8	-10.000	-20.000	10.000
30	9	-5.000	-10.000	5.000
30	10	-15.000	-5.000	-10.000
50	16	-5.000	-5.000	0.000
50	17	-25.000	-25.000	0.000
50	18	-30.000	-5.000	-25.000
50	19	-5.000	-25.000	20.000
50	20	-5.000	-25.000	20.000
100	B043	-25.000	-20.000	-5.000
100	B044	-5.000	-25.000	20.000
100	B045	-5.000	-5.000	0.000
100	B046	-10.000	-20.000	10.000
100	B047	-20.000	-5.000	-15.000
100	B048	-15.000	-5.000	-10.000
100	B049	-15.000	-20.000	5.000
100	B050	-25.000	-5.000	-20.000
100	B051	-5.000	-20.000	15.000
100	B052	-5.000	-10.000	5.000
100	B053	-5.000	-15.000	10.000
100	B054	-20.000	-20.000	0.000
100	B055	-10.000	-5.000	-5.000
100	B056	-5.000	-5.000	0.000
100	B057	-20.000	-5.000	-15.000
100	B058	-5.000	-15.000	10.000
100	B059	-15.000	-5.000	-10.000
100	B060	-5.000	-5.000	0.000
100	B061	-30.000	-20.000	-10.000
100	B062	-15.000	-5.000	-10.000
100	B063	-5.000	-15.000	10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	20.000
	Average	-11.351	-11.216	-0.135
	Min	-30.000	-25.000	-25.000
	Std Dev	8.049	7.674	10.768

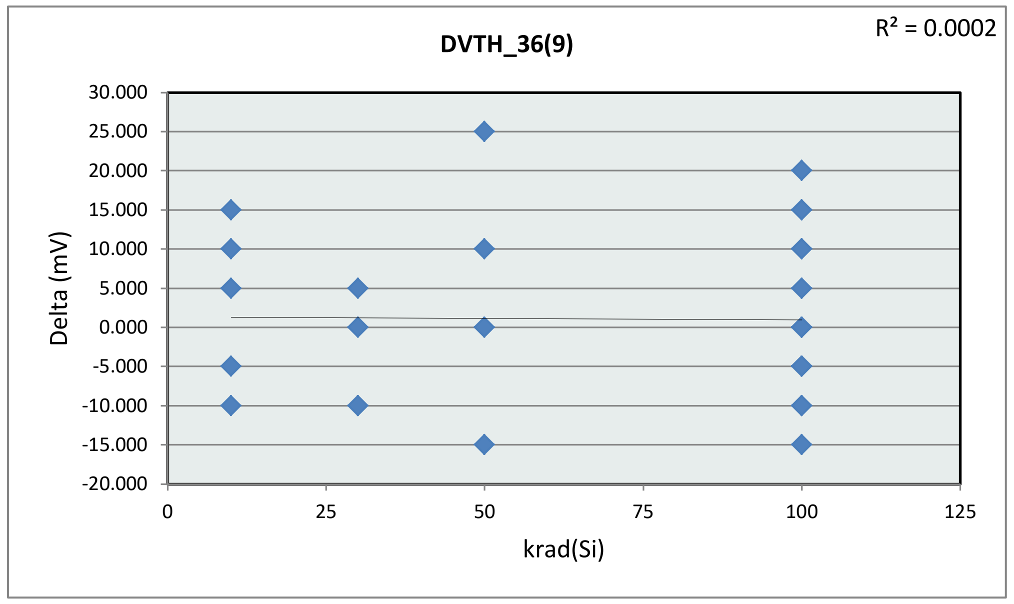


	VIDL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-20.000	-25.000	-25.000
Average	-5.000	-10.000	-17.000	-11.591
Max	-5.000	-5.000	-5.000	-5.000
UL				

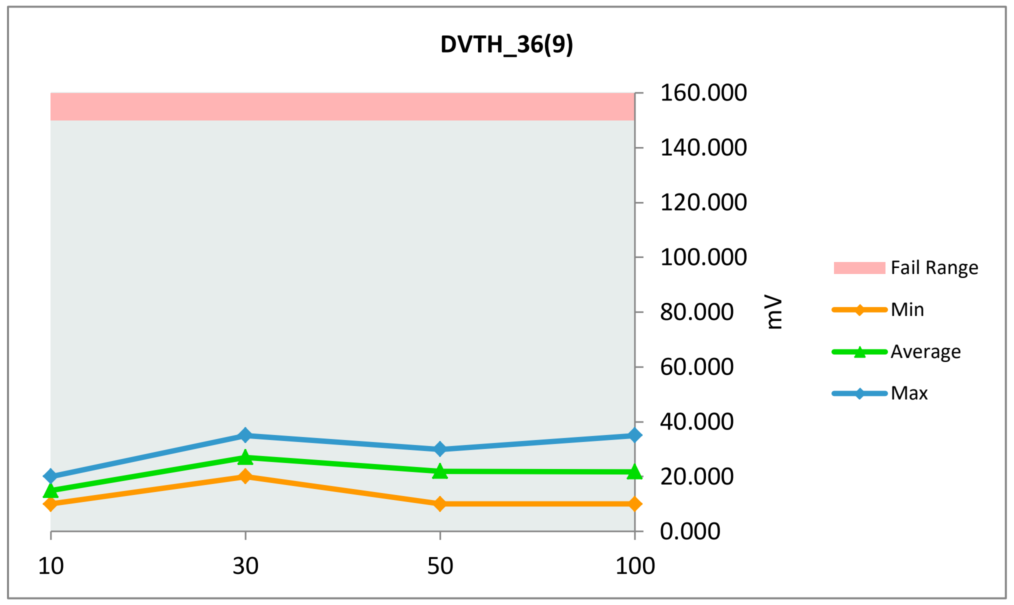


TID Report
SN55LVCP22A-SP

		DVTH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	30.000	15.000	15.000
10	7	20.000	10.000	10.000
10	8	10.000	15.000	-5.000
10	9	10.000	20.000	-10.000
10	10	20.000	15.000	5.000
30	6	10.000	20.000	-10.000
30	7	35.000	35.000	0.000
30	8	25.000	25.000	0.000
30	9	30.000	25.000	5.000
30	10	20.000	30.000	-10.000
50	16	20.000	10.000	10.000
50	17	30.000	30.000	0.000
50	18	35.000	10.000	25.000
50	19	30.000	30.000	0.000
50	20	15.000	30.000	-15.000
100	B043	45.000	25.000	20.000
100	B044	25.000	30.000	-5.000
100	B045	10.000	10.000	0.000
100	B046	15.000	25.000	-10.000
100	B047	25.000	25.000	0.000
100	B048	20.000	10.000	10.000
100	B049	20.000	35.000	-15.000
100	B050	30.000	20.000	10.000
100	B051	20.000	25.000	-5.000
100	B052	10.000	15.000	-5.000
100	B053	10.000	20.000	-10.000
100	B054	40.000	25.000	15.000
100	B055	15.000	10.000	5.000
100	B056	10.000	15.000	-5.000
100	B057	25.000	10.000	15.000
100	B058	25.000	35.000	-10.000
100	B059	20.000	15.000	5.000
100	B060	25.000	25.000	0.000
100	B061	35.000	25.000	10.000
100	B062	30.000	30.000	0.000
100	B063	20.000	20.000	0.000
100	B064	25.000	30.000	-5.000
	Max	45.000	35.000	25.000
	Average	22.703	21.622	1.081
	Min	10.000	10.000	-15.000
	Std Dev	9.098	8.084	9.799

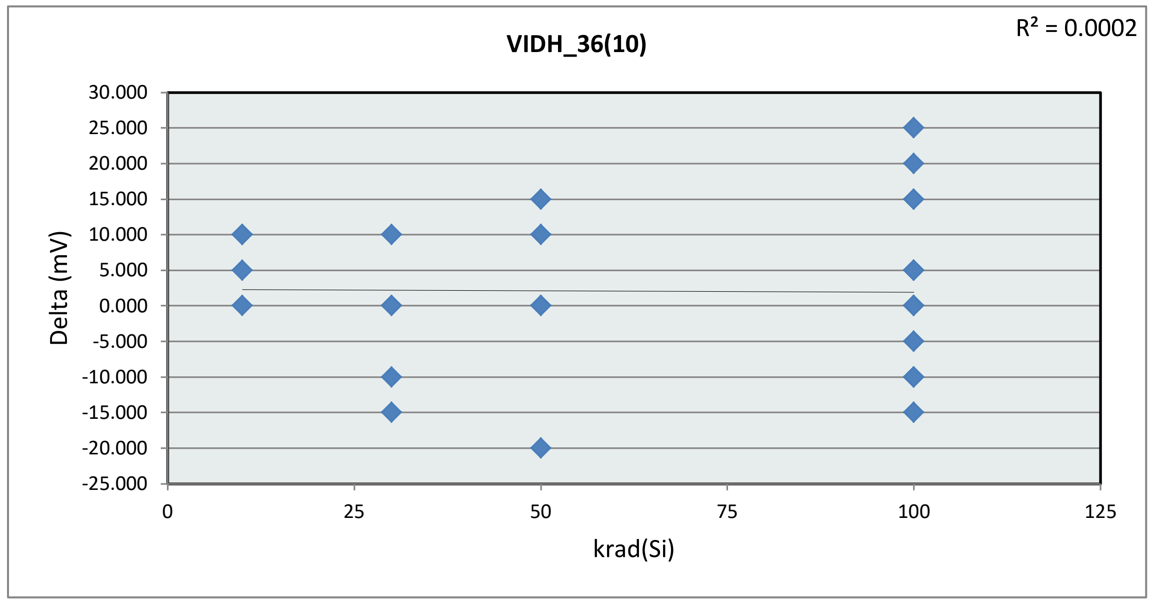


	DVTH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	20.000	10.000	10.000
Average	15.000	27.000	22.000	21.818
Max	20.000	35.000	30.000	35.000
UL	150.000	150.000	150.000	150.000

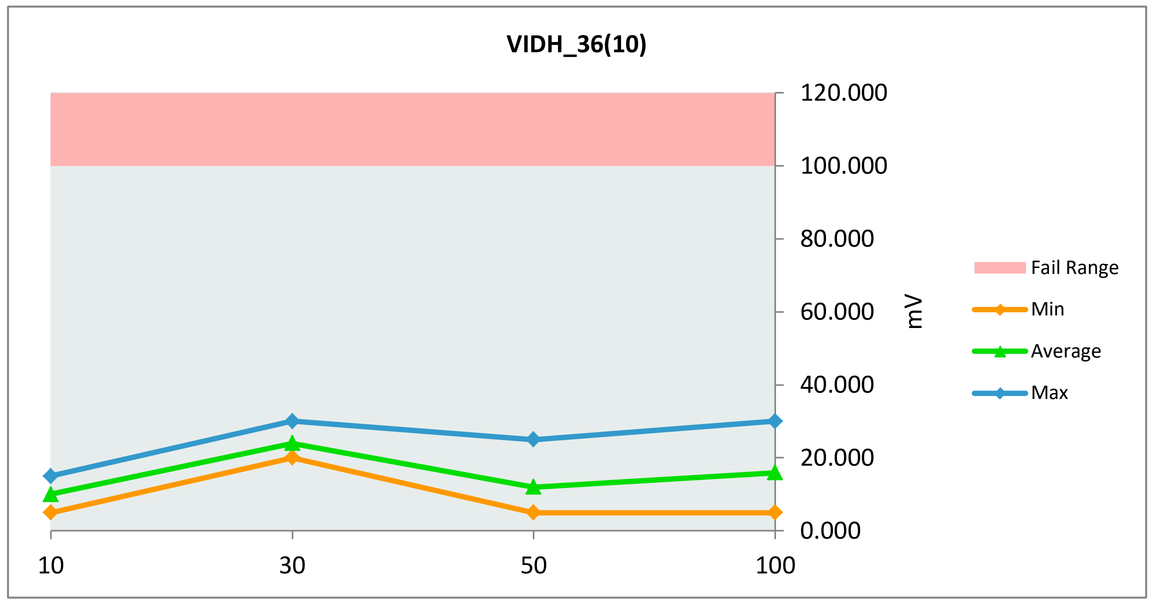


HDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	20.000	15.000	5.000
10	7	15.000	15.000	0.000
10	8	15.000	5.000	10.000
10	9	20.000	10.000	10.000
10	10	15.000	5.000	10.000
30	6	20.000	20.000	0.000
30	7	30.000	30.000	0.000
30	8	30.000	20.000	10.000
30	9	20.000	30.000	-10.000
30	10	5.000	20.000	-15.000
50	16	25.000	15.000	10.000
50	17	5.000	5.000	0.000
50	18	5.000	25.000	-20.000
50	19	25.000	10.000	15.000
50	20	5.000	5.000	0.000
100	B043	30.000	5.000	25.000
100	B044	20.000	5.000	15.000
100	B045	5.000	20.000	-15.000
100	B046	15.000	25.000	-10.000
100	B047	5.000	15.000	-10.000
100	B048	10.000	5.000	5.000
100	B049	20.000	15.000	5.000
100	B050	5.000	10.000	-5.000
100	B051	25.000	5.000	20.000
100	B052	20.000	5.000	15.000
100	B053	10.000	20.000	-10.000
100	B054	30.000	5.000	25.000
100	B055	25.000	25.000	0.000
100	B056	25.000	20.000	5.000
100	B057	10.000	5.000	5.000
100	B058	20.000	30.000	-10.000
100	B059	25.000	25.000	0.000
100	B060	30.000	25.000	5.000
100	B061	10.000	10.000	0.000
100	B062	15.000	20.000	-5.000
100	B063	15.000	25.000	-10.000
100	B064	30.000	30.000	0.000
	Max	30.000	30.000	25.000
	Average	17.703	15.676	2.027
	Min	5.000	5.000	-20.000
	Std Dev	8.628	8.910	10.958

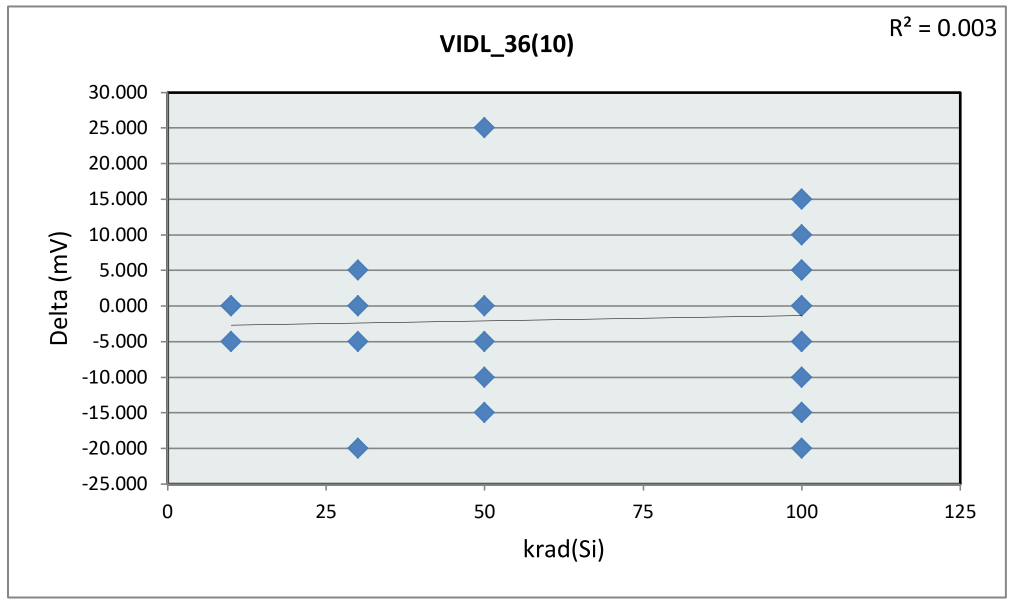


	VIDH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	20.000	5.000	5.000
Average	10.000	24.000	12.000	15.909
Max	15.000	30.000	25.000	30.000
UL	100.000	100.000	100.000	100.000

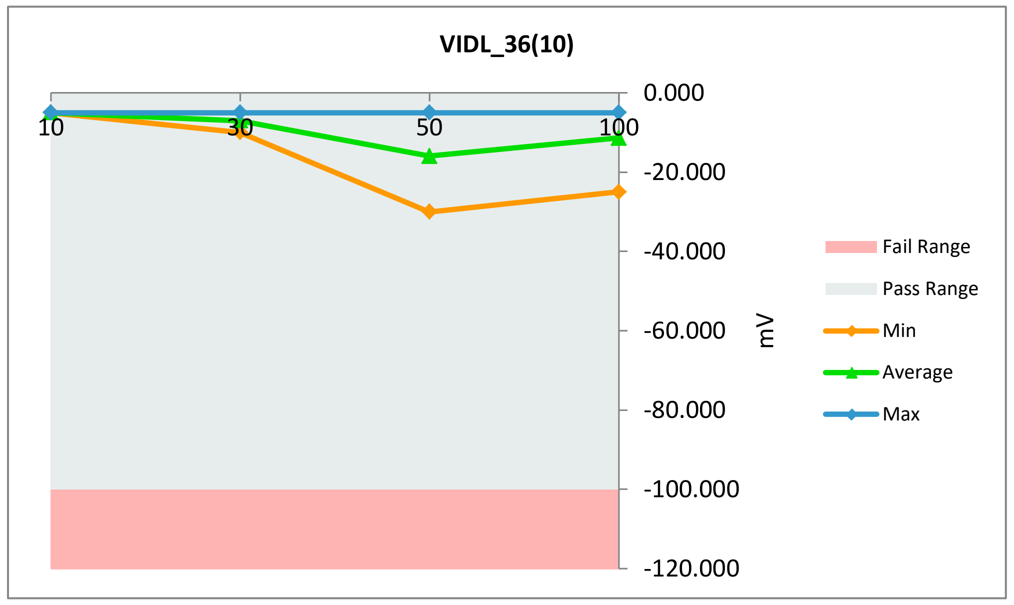


HDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-10.000	-5.000	-5.000
10	8	-5.000	-5.000	0.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-15.000	-10.000	-5.000
30	8	-5.000	-10.000	5.000
30	9	-5.000	-5.000	0.000
30	10	-25.000	-5.000	-20.000
50	16	-5.000	-5.000	0.000
50	17	-30.000	-25.000	-5.000
50	18	-20.000	-5.000	-15.000
50	19	-5.000	-30.000	25.000
50	20	-25.000	-15.000	-10.000
100	B043	-20.000	-25.000	5.000
100	B044	-5.000	-20.000	15.000
100	B045	-20.000	-5.000	-15.000
100	B046	-20.000	-15.000	-5.000
100	B047	-25.000	-5.000	-20.000
100	B048	-15.000	-20.000	5.000
100	B049	-10.000	-20.000	10.000
100	B050	-20.000	-15.000	-5.000
100	B051	-5.000	-20.000	15.000
100	B052	-5.000	-10.000	5.000
100	B053	-20.000	-5.000	-15.000
100	B054	-10.000	-20.000	10.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-10.000	-15.000	5.000
100	B058	-10.000	-10.000	0.000
100	B059	-10.000	-5.000	-5.000
100	B060	-5.000	-5.000	0.000
100	B061	-20.000	-10.000	-10.000
100	B062	-20.000	-5.000	-15.000
100	B063	-15.000	-5.000	-10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-12.297	-10.541	-1.757
	Min	-30.000	-30.000	-20.000
	Std Dev	7.691	7.339	9.805



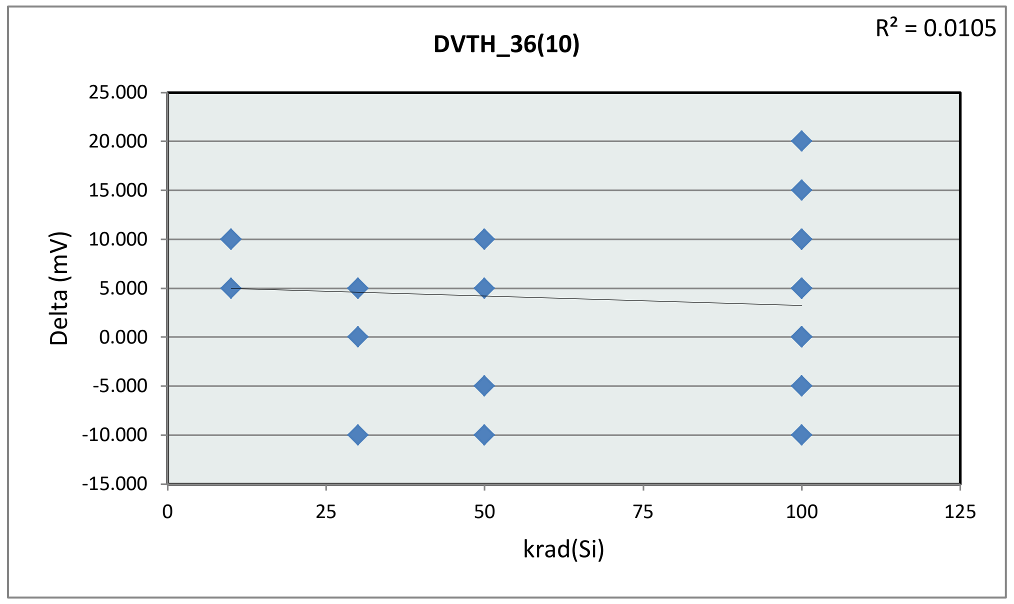
	VIDL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-10.000	-30.000	-25.000
Average	-5.000	-7.000	-16.000	-11.364
Max	-5.000	-5.000	-5.000	-5.000
UL				



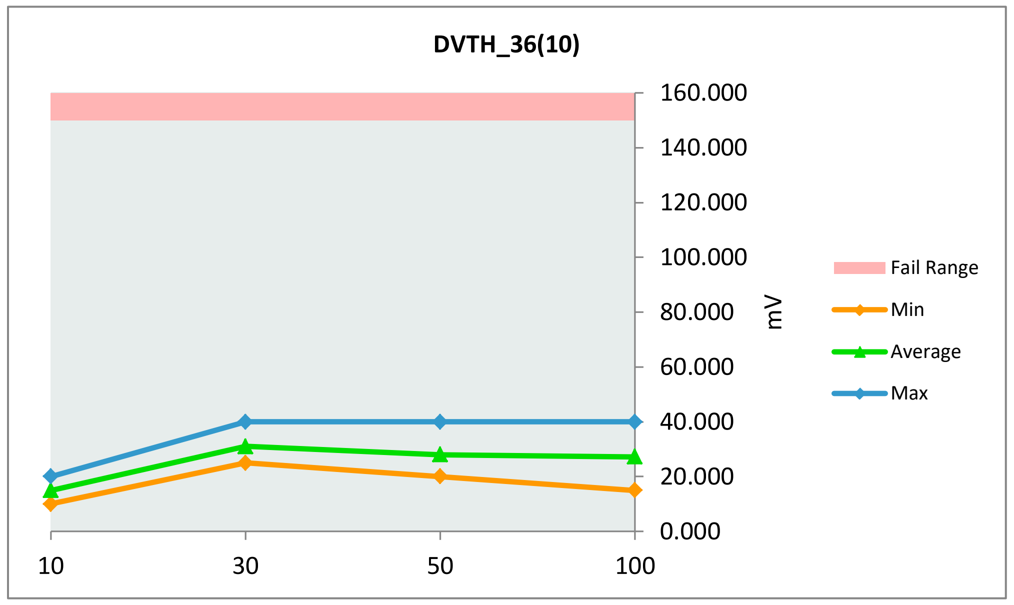
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_36(10)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	mV	mV	
Max Limit	150	150	
Min Limit			

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	30.000	20.000	10.000
10	7	25.000	20.000	5.000
10	8	20.000	10.000	10.000
10	9	25.000	15.000	10.000
10	10	20.000	10.000	10.000
30	6	25.000	25.000	0.000
30	7	45.000	40.000	5.000
30	8	35.000	30.000	5.000
30	9	25.000	35.000	-10.000
30	10	30.000	25.000	5.000
50	16	30.000	20.000	10.000
50	17	35.000	30.000	5.000
50	18	25.000	30.000	-5.000
50	19	30.000	40.000	-10.000
50	20	30.000	20.000	10.000
100	B043	50.000	30.000	20.000
100	B044	25.000	25.000	0.000
100	B045	25.000	25.000	0.000
100	B046	35.000	40.000	-5.000
100	B047	30.000	20.000	10.000
100	B048	25.000	25.000	0.000
100	B049	30.000	35.000	-5.000
100	B050	25.000	25.000	0.000
100	B051	30.000	25.000	5.000
100	B052	25.000	15.000	10.000
100	B053	30.000	25.000	5.000
100	B054	40.000	25.000	15.000
100	B055	30.000	30.000	0.000
100	B056	30.000	25.000	5.000
100	B057	20.000	20.000	0.000
100	B058	30.000	40.000	-10.000
100	B059	35.000	30.000	5.000
100	B060	35.000	30.000	5.000
100	B061	30.000	20.000	10.000
100	B062	35.000	25.000	10.000
100	B063	30.000	30.000	0.000
100	B064	35.000	35.000	0.000
	Max	50.000	40.000	20.000
	Average	30.000	26.216	3.784
	Min	20.000	10.000	-10.000
	Std Dev	6.346	7.764	6.913

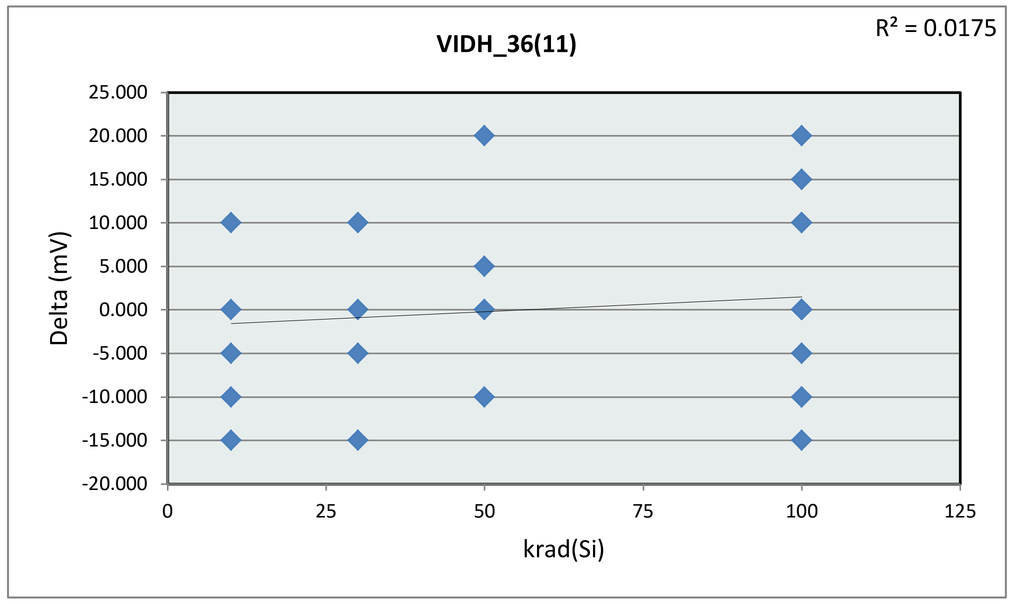


	DVTH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	25.000	20.000	15.000
Average	15.000	31.000	28.000	27.273
Max	20.000	40.000	40.000	40.000
UL	150.000	150.000	150.000	150.000

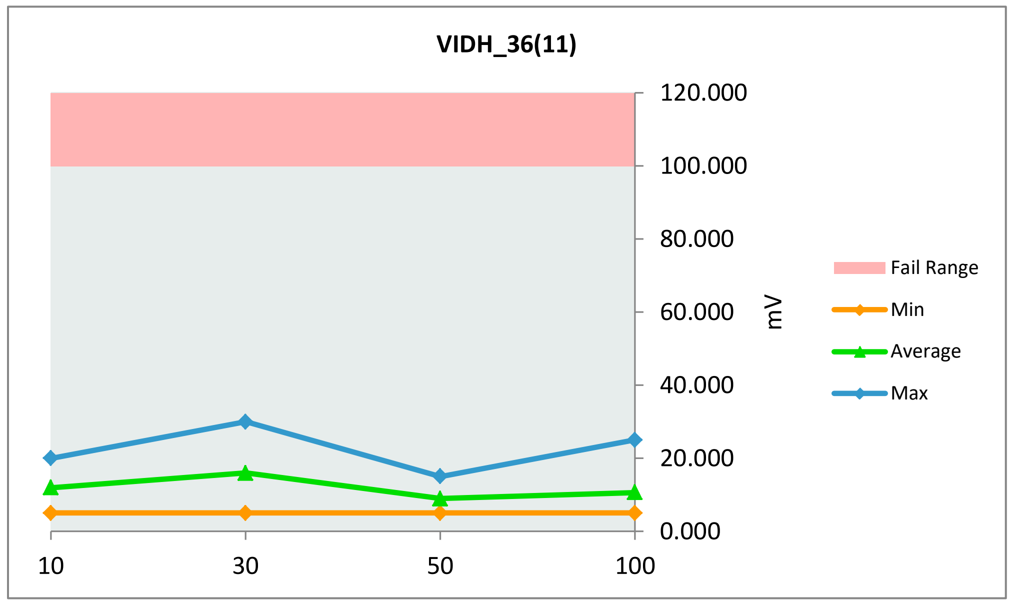


HDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	20.000	10.000	10.000
10	7	5.000	5.000	0.000
10	8	5.000	15.000	-10.000
10	9	5.000	20.000	-15.000
10	10	5.000	10.000	-5.000
30	6	5.000	10.000	-5.000
30	7	30.000	30.000	0.000
30	8	15.000	5.000	10.000
30	9	25.000	15.000	10.000
30	10	5.000	20.000	-15.000
50	16	15.000	15.000	0.000
50	17	5.000	5.000	0.000
50	18	5.000	15.000	-10.000
50	19	25.000	5.000	20.000
50	20	10.000	5.000	5.000
100	B043	20.000	5.000	15.000
100	B044	5.000	5.000	0.000
100	B045	5.000	5.000	0.000
100	B046	15.000	15.000	0.000
100	B047	5.000	20.000	-15.000
100	B048	5.000	10.000	-5.000
100	B049	5.000	15.000	-10.000
100	B050	5.000	5.000	0.000
100	B051	20.000	5.000	15.000
100	B052	15.000	5.000	10.000
100	B053	5.000	5.000	0.000
100	B054	25.000	5.000	20.000
100	B055	5.000	15.000	-10.000
100	B056	15.000	5.000	10.000
100	B057	5.000	5.000	0.000
100	B058	25.000	25.000	0.000
100	B059	5.000	5.000	0.000
100	B060	20.000	20.000	0.000
100	B061	5.000	5.000	0.000
100	B062	15.000	25.000	-10.000
100	B063	15.000	5.000	10.000
100	B064	20.000	25.000	-5.000
	Max	30.000	30.000	20.000
	Average	11.892	11.351	0.541
	Min	5.000	5.000	-15.000
	Std Dev	8.024	7.514	9.338

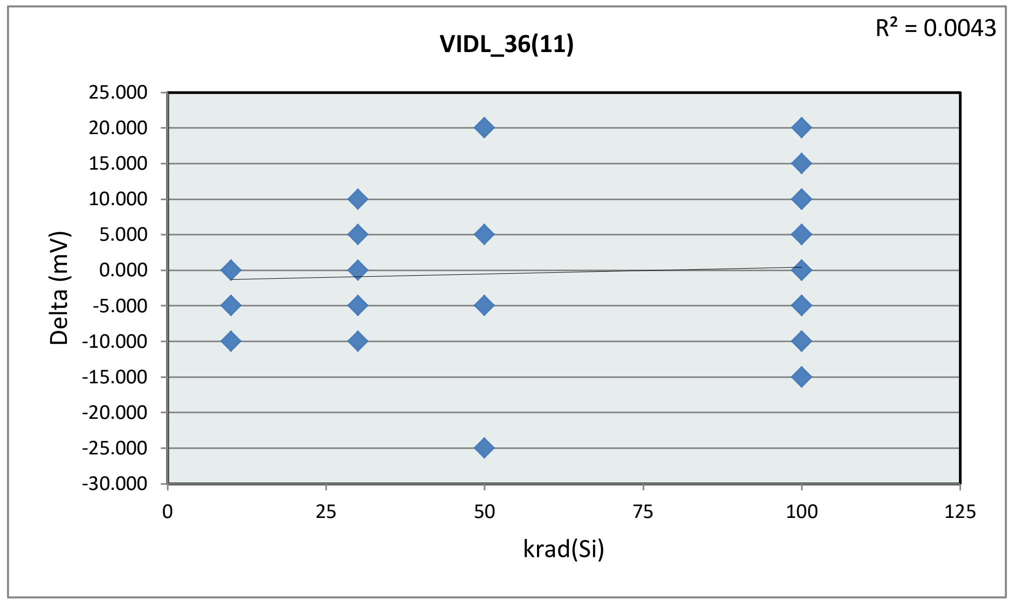


	VIDH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	12.000	16.000	9.000	10.682
Max	20.000	30.000	15.000	25.000
UL	100.000	100.000	100.000	100.000

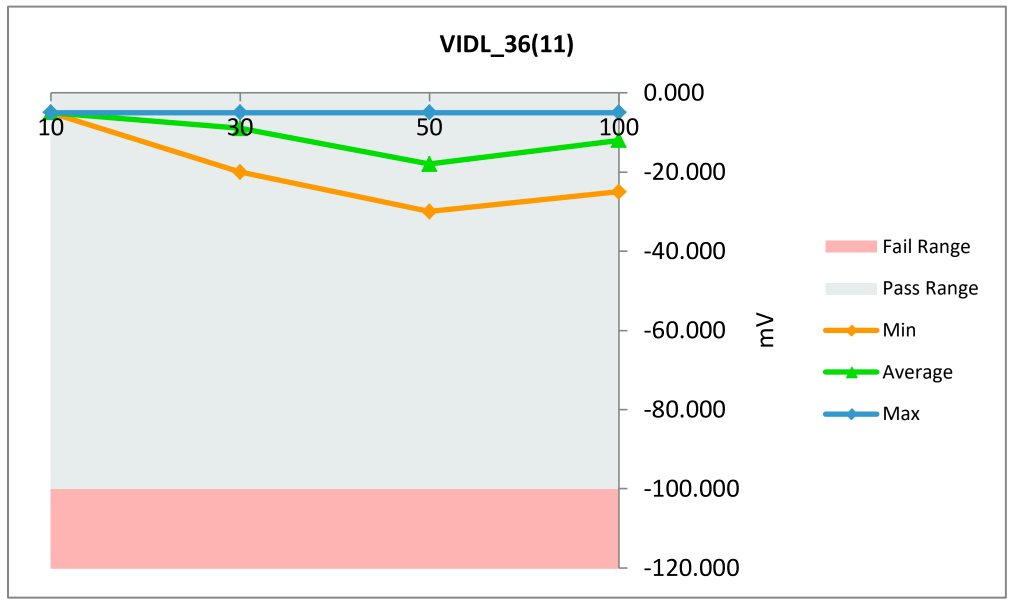


HDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-15.000	-5.000	-10.000
10	8	-5.000	-5.000	0.000
10	9	-10.000	-5.000	-5.000
10	10	-5.000	-5.000	0.000
30	6	-10.000	-5.000	-5.000
30	7	-5.000	-10.000	5.000
30	8	-10.000	-20.000	10.000
30	9	-5.000	-5.000	0.000
30	10	-15.000	-5.000	-10.000
50	16	-10.000	-5.000	-5.000
50	17	-25.000	-30.000	5.000
50	18	-30.000	-5.000	-25.000
50	19	-5.000	-25.000	20.000
50	20	-5.000	-25.000	20.000
100	B043	-20.000	-20.000	0.000
100	B044	-5.000	-25.000	20.000
100	B045	-10.000	-5.000	-5.000
100	B046	-10.000	-20.000	10.000
100	B047	-20.000	-5.000	-15.000
100	B048	-5.000	-5.000	0.000
100	B049	-15.000	-20.000	5.000
100	B050	-25.000	-10.000	-15.000
100	B051	-5.000	-20.000	15.000
100	B052	-5.000	-15.000	10.000
100	B053	-10.000	-15.000	5.000
100	B054	-15.000	-20.000	5.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-20.000	-5.000	-15.000
100	B058	-5.000	-15.000	10.000
100	B059	-15.000	-5.000	-10.000
100	B060	-10.000	-5.000	-5.000
100	B061	-30.000	-20.000	-10.000
100	B062	-15.000	-5.000	-10.000
100	B063	-5.000	-15.000	10.000
100	B064	-10.000	-5.000	-5.000
	Max	-5.000	-5.000	20.000
	Average	-11.622	-11.486	-0.135
	Min	-30.000	-30.000	-25.000
	Std Dev	7.365	7.981	10.573

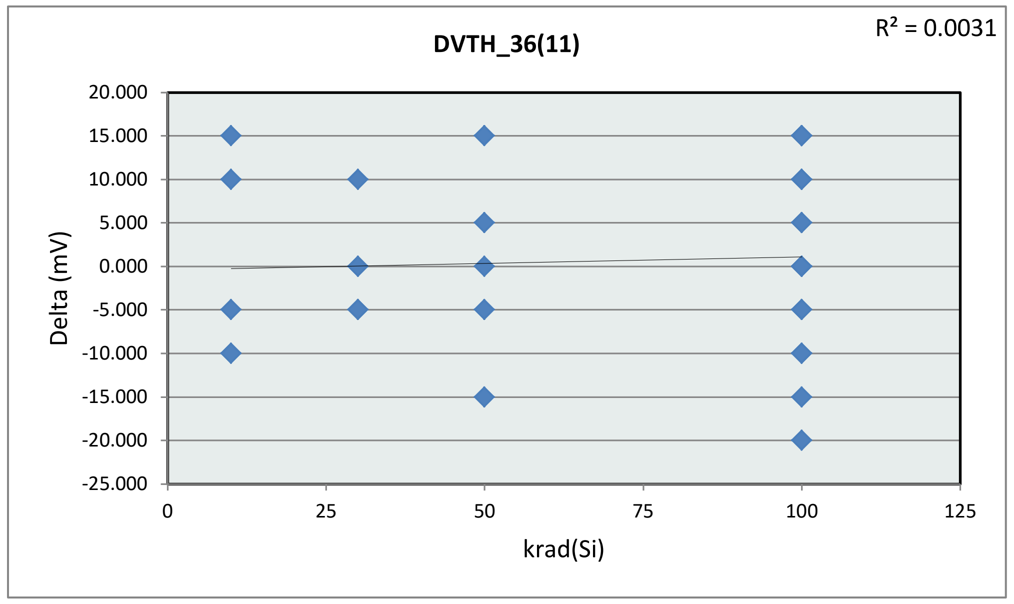


	VIDL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-20.000	-30.000	-25.000
Average	-5.000	-9.000	-18.000	-12.045
Max	-5.000	-5.000	-5.000	-5.000
UL				

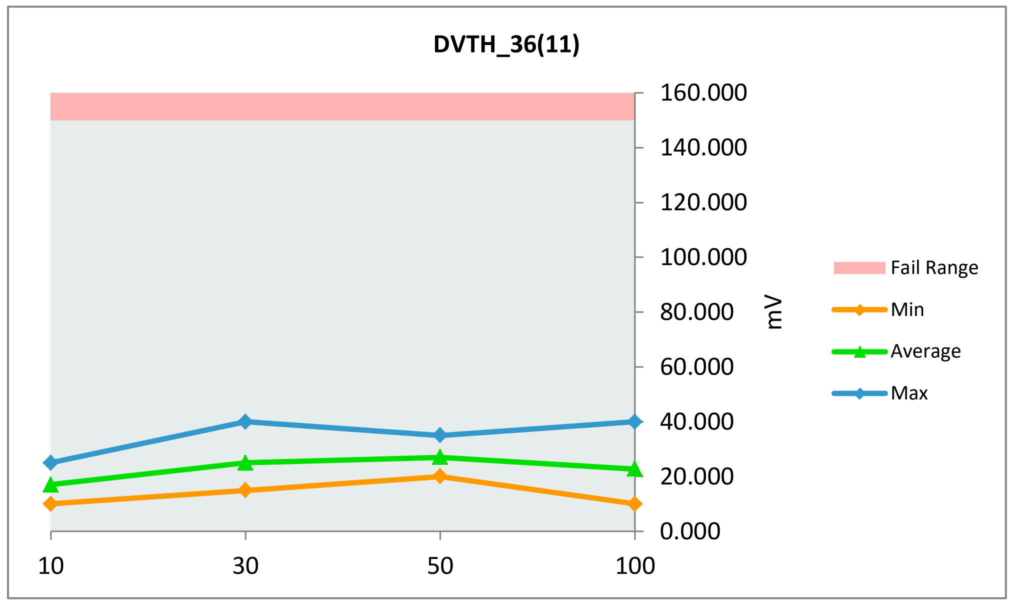


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	30.000	15.000	15.000
10	7	20.000	10.000	10.000
10	8	10.000	20.000	-10.000
10	9	15.000	25.000	-10.000
10	10	10.000	15.000	-5.000
30	6	15.000	15.000	0.000
30	7	35.000	40.000	-5.000
30	8	25.000	25.000	0.000
30	9	30.000	20.000	10.000
30	10	20.000	25.000	-5.000
50	16	25.000	20.000	5.000
50	17	30.000	35.000	-5.000
50	18	35.000	20.000	15.000
50	19	30.000	30.000	0.000
50	20	15.000	30.000	-15.000
100	B043	40.000	25.000	15.000
100	B044	10.000	30.000	-20.000
100	B045	15.000	10.000	5.000
100	B046	25.000	35.000	-10.000
100	B047	25.000	25.000	0.000
100	B048	10.000	15.000	-5.000
100	B049	20.000	35.000	-15.000
100	B050	30.000	15.000	15.000
100	B051	25.000	25.000	0.000
100	B052	20.000	20.000	0.000
100	B053	15.000	20.000	-5.000
100	B054	40.000	25.000	15.000
100	B055	10.000	20.000	-10.000
100	B056	20.000	10.000	10.000
100	B057	25.000	10.000	15.000
100	B058	30.000	40.000	-10.000
100	B059	20.000	10.000	10.000
100	B060	30.000	25.000	5.000
100	B061	35.000	25.000	10.000
100	B062	30.000	30.000	0.000
100	B063	20.000	20.000	0.000
100	B064	30.000	30.000	0.000
	Max	40.000	40.000	15.000
	Average	23.514	22.838	0.676
	Min	10.000	10.000	-20.000
	Std Dev	8.649	8.378	9.730

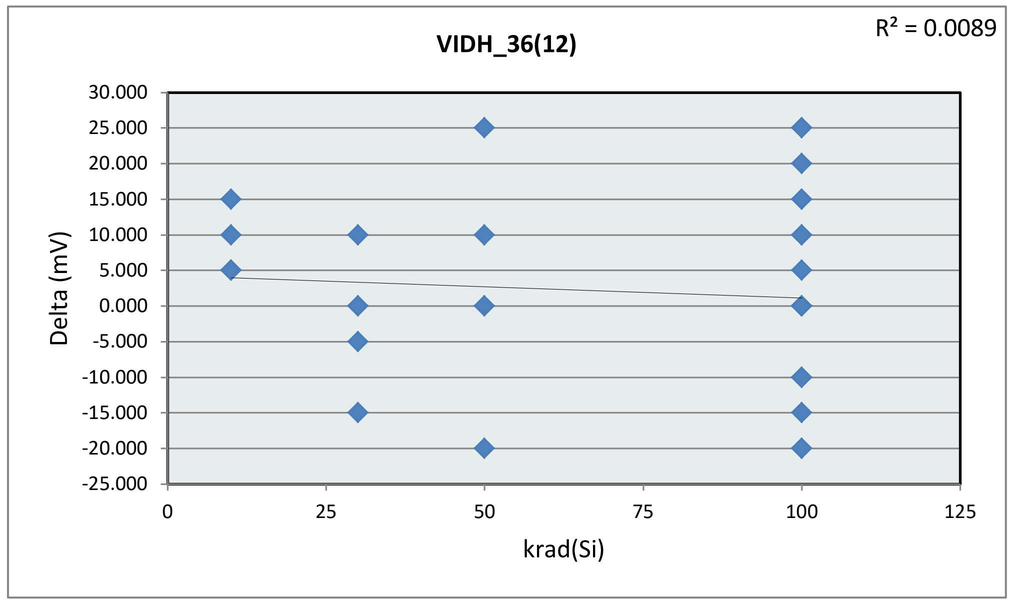


	DVTH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	15.000	20.000	10.000
Average	17.000	25.000	27.000	22.727
Max	25.000	40.000	35.000	40.000
UL	150.000	150.000	150.000	150.000

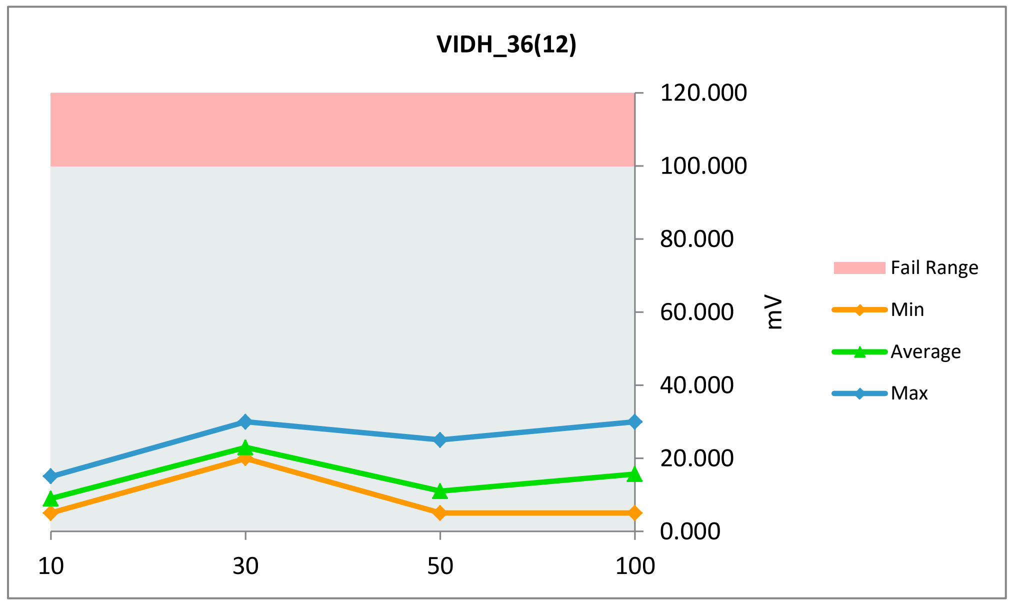


HDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	20.000	15.000	5.000
10	7	15.000	5.000	10.000
10	8	15.000	10.000	5.000
10	9	20.000	5.000	15.000
10	10	15.000	10.000	5.000
30	6	20.000	20.000	0.000
30	7	30.000	30.000	0.000
30	8	30.000	20.000	10.000
30	9	20.000	25.000	-5.000
30	10	5.000	20.000	-15.000
50	16	25.000	15.000	10.000
50	17	5.000	5.000	0.000
50	18	5.000	25.000	-20.000
50	19	30.000	5.000	25.000
50	20	5.000	5.000	0.000
100	B043	30.000	5.000	25.000
100	B044	20.000	5.000	15.000
100	B045	5.000	15.000	-10.000
100	B046	5.000	25.000	-20.000
100	B047	5.000	15.000	-10.000
100	B048	5.000	5.000	0.000
100	B049	25.000	15.000	10.000
100	B050	5.000	5.000	0.000
100	B051	25.000	5.000	20.000
100	B052	20.000	5.000	15.000
100	B053	5.000	25.000	-20.000
100	B054	30.000	5.000	25.000
100	B055	25.000	25.000	0.000
100	B056	20.000	20.000	0.000
100	B057	10.000	10.000	0.000
100	B058	20.000	30.000	-10.000
100	B059	25.000	25.000	0.000
100	B060	30.000	20.000	10.000
100	B061	15.000	15.000	0.000
100	B062	5.000	20.000	-15.000
100	B063	15.000	25.000	-10.000
100	B064	30.000	25.000	5.000
	Max	30.000	30.000	25.000
	Average	17.162	15.135	2.027
	Min	5.000	5.000	-20.000
	Std Dev	9.468	8.619	12.330



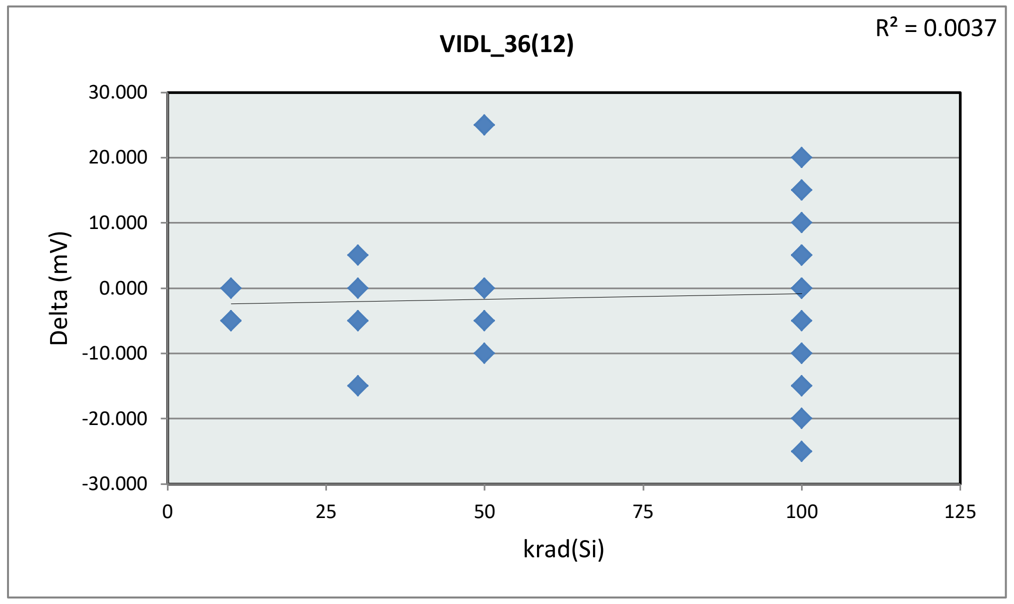
	VIDH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	20.000	5.000	5.000
Average	9.000	23.000	11.000	15.682
Max	15.000	30.000	25.000	30.000
UL	100.000	100.000	100.000	100.000



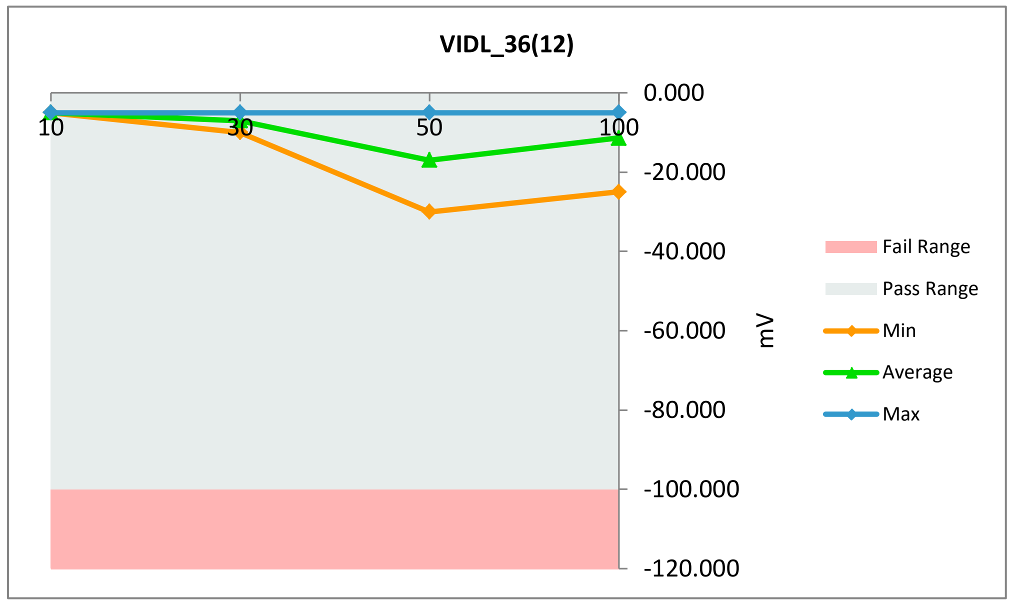
HDR UnBiased TID Report
SN55LVCP22A-SP

	VIDL_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-10.000	-5.000	-5.000
10	8	-10.000	-5.000	-5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-15.000	-10.000	-5.000
30	8	-5.000	-10.000	5.000
30	9	-10.000	-5.000	-5.000
30	10	-20.000	-5.000	-15.000
50	16	-5.000	-5.000	0.000
50	17	-30.000	-25.000	-5.000
50	18	-15.000	-5.000	-10.000
50	19	-5.000	-30.000	25.000
50	20	-20.000	-20.000	0.000
100	B043	-15.000	-20.000	5.000
100	B044	-5.000	-20.000	15.000
100	B045	-25.000	-5.000	-20.000
100	B046	-20.000	-15.000	-5.000
100	B047	-30.000	-5.000	-25.000
100	B048	-10.000	-20.000	10.000
100	B049	-5.000	-20.000	15.000
100	B050	-25.000	-15.000	-10.000
100	B051	-5.000	-25.000	20.000
100	B052	-5.000	-10.000	5.000
100	B053	-20.000	-5.000	-15.000
100	B054	-15.000	-20.000	5.000
100	B055	-5.000	-5.000	0.000
100	B056	-5.000	-5.000	0.000
100	B057	-10.000	-15.000	5.000
100	B058	-5.000	-10.000	5.000
100	B059	-5.000	-5.000	0.000
100	B060	-5.000	-5.000	0.000
100	B061	-20.000	-10.000	-10.000
100	B062	-20.000	-5.000	-15.000
100	B063	-15.000	-5.000	-10.000
100	B064	-5.000	-5.000	0.000
	Max	-5.000	-5.000	25.000
	Average	-12.027	-10.676	-1.351
	Min	-30.000	-30.000	-25.000
	Std Dev	7.858	7.469	10.452



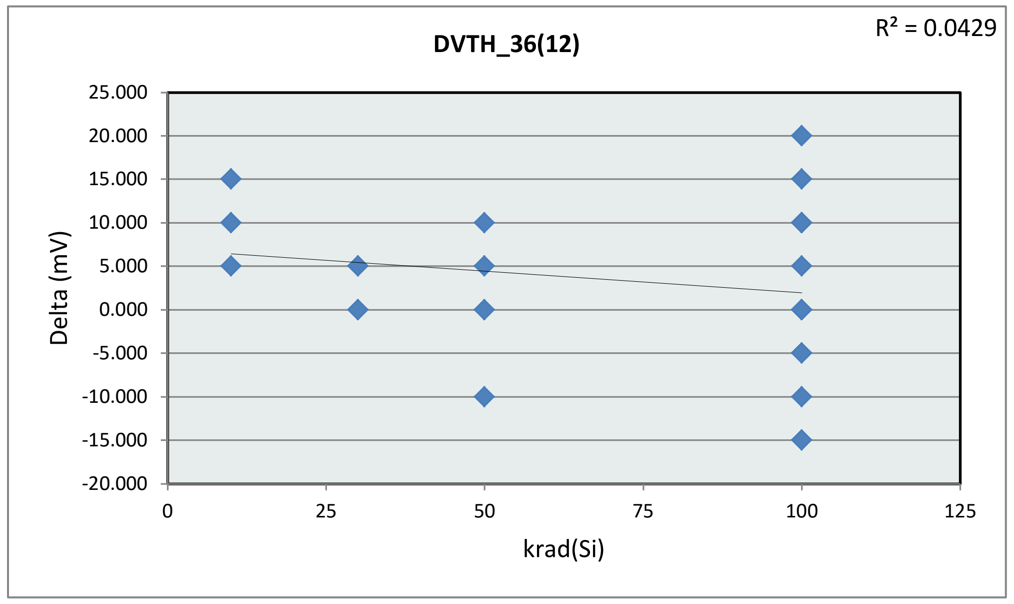
	VIDL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-5.000	-10.000	-30.000	-25.000
Average	-5.000	-7.000	-17.000	-11.364
Max	-5.000	-5.000	-5.000	-5.000
UL				



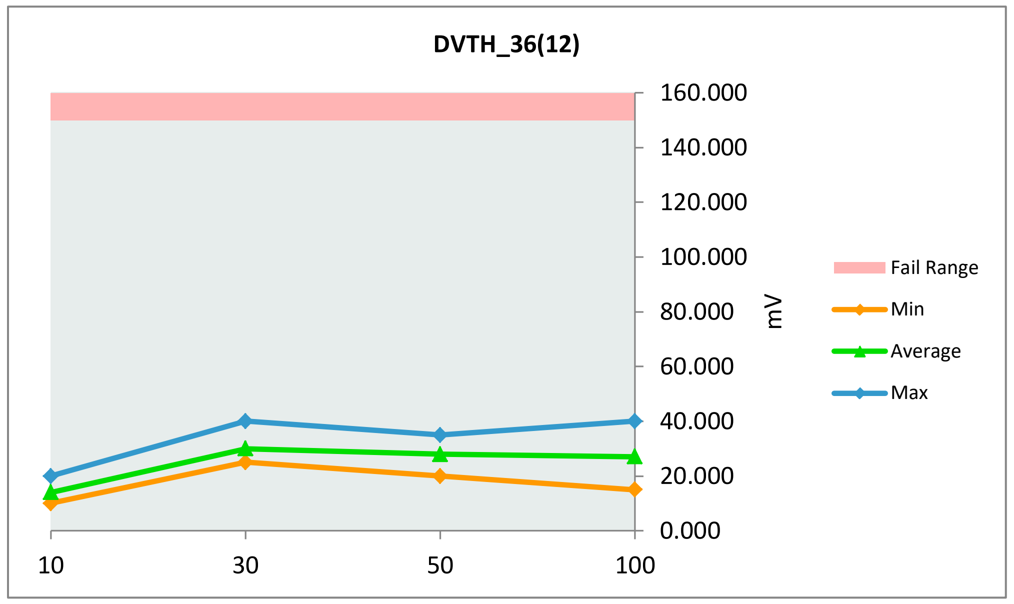
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	30.000	20.000	10.000
10	7	25.000	10.000	15.000
10	8	25.000	15.000	10.000
10	9	25.000	10.000	15.000
10	10	20.000	15.000	5.000
30	6	25.000	25.000	0.000
30	7	45.000	40.000	5.000
30	8	35.000	30.000	5.000
30	9	30.000	30.000	0.000
30	10	25.000	25.000	0.000
50	16	30.000	20.000	10.000
50	17	35.000	30.000	5.000
50	18	20.000	30.000	-10.000
50	19	35.000	35.000	0.000
50	20	25.000	25.000	0.000
100	B043	45.000	25.000	20.000
100	B044	25.000	25.000	0.000
100	B045	30.000	20.000	10.000
100	B046	25.000	40.000	-15.000
100	B047	35.000	20.000	15.000
100	B048	15.000	25.000	-10.000
100	B049	30.000	35.000	-5.000
100	B050	30.000	20.000	10.000
100	B051	30.000	30.000	0.000
100	B052	25.000	15.000	10.000
100	B053	25.000	30.000	-5.000
100	B054	45.000	25.000	20.000
100	B055	30.000	30.000	0.000
100	B056	25.000	25.000	0.000
100	B057	20.000	25.000	-5.000
100	B058	25.000	40.000	-15.000
100	B059	30.000	30.000	0.000
100	B060	35.000	25.000	10.000
100	B061	35.000	25.000	10.000
100	B062	25.000	25.000	0.000
100	B063	30.000	30.000	0.000
100	B064	35.000	30.000	5.000
	Max	45.000	40.000	20.000
	Average	29.189	25.811	3.378
	Min	15.000	10.000	-15.000
	Std Dev	6.823	7.408	8.665

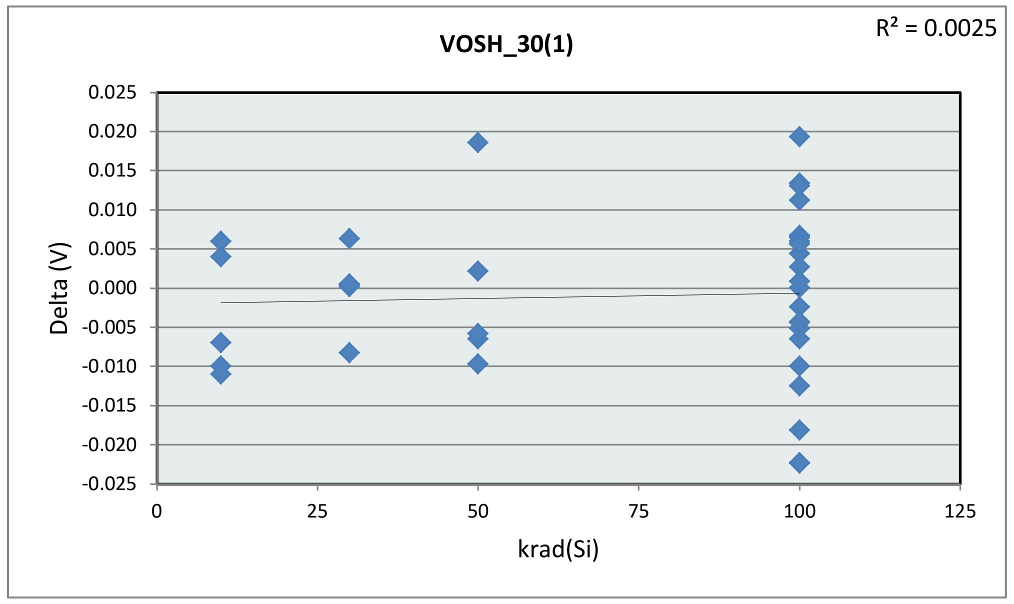


	DVTH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	25.000	20.000	15.000
Average	14.000	30.000	28.000	27.045
Max	20.000	40.000	35.000	40.000
UL	150.000	150.000	150.000	150.000

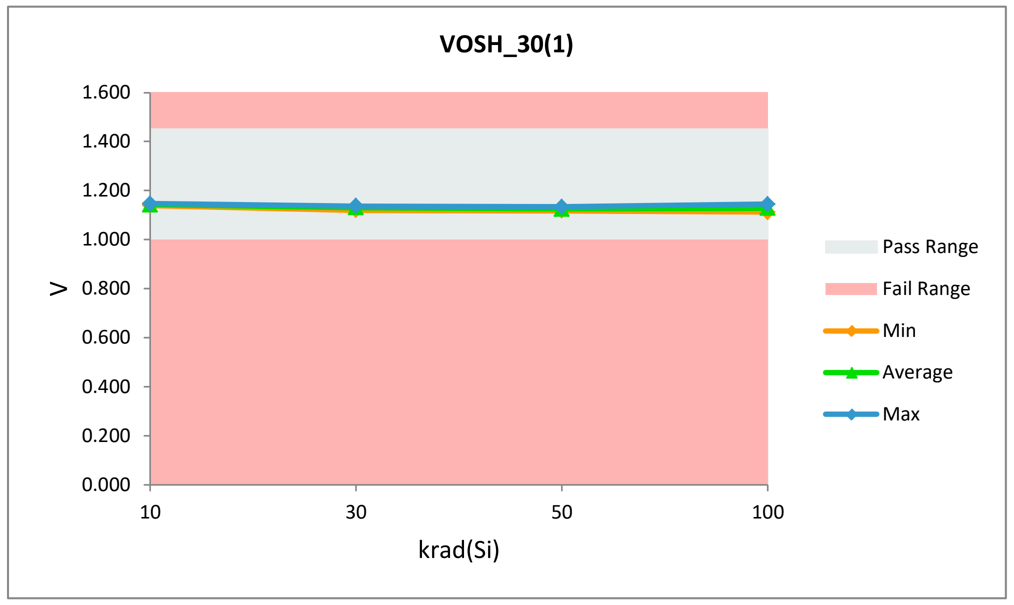


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.129	1.139	-0.010
10	7	1.140	1.147	-0.007
10	8	1.148	1.144	0.004
10	9	1.148	1.142	0.006
10	10	1.128	1.139	-0.011
30	6	1.135	1.135	0.000
30	7	1.120	1.120	0.000
30	8	1.132	1.132	0.000
30	9	1.137	1.131	0.006
30	10	1.129	1.137	-0.008
50	16	1.128	1.134	-0.006
50	17	1.118	1.128	-0.010
50	18	1.120	1.126	-0.006
50	19	1.120	1.118	0.002
50	20	1.139	1.120	0.019
100	B043	1.124	1.142	-0.018
100	B044	1.132	1.128	0.004
100	B045	1.140	1.127	0.013
100	B046	1.125	1.125	0.000
100	B047	1.122	1.132	-0.010
100	B048	1.118	1.140	-0.022
100	B049	1.123	1.112	0.011
100	B050	1.123	1.125	-0.002
100	B051	1.129	1.122	0.007
100	B052	1.133	1.120	0.013
100	B053	1.126	1.123	0.003
100	B054	1.116	1.123	-0.007
100	B055	1.124	1.129	-0.005
100	B056	1.135	1.134	0.001
100	B057	1.145	1.126	0.019
100	B058	1.124	1.118	0.006
100	B059	1.130	1.124	0.006
100	B060	1.142	1.136	0.006
100	B061	1.123	1.145	-0.022
100	B062	1.123	1.127	-0.004
100	B063	1.126	1.130	-0.004
100	B064	1.128	1.140	-0.012
	Max	1.148	1.147	0.019
	Average	1.129	1.130	-0.001
	Min	1.116	1.112	-0.022
	Std Dev	0.009	0.009	0.010

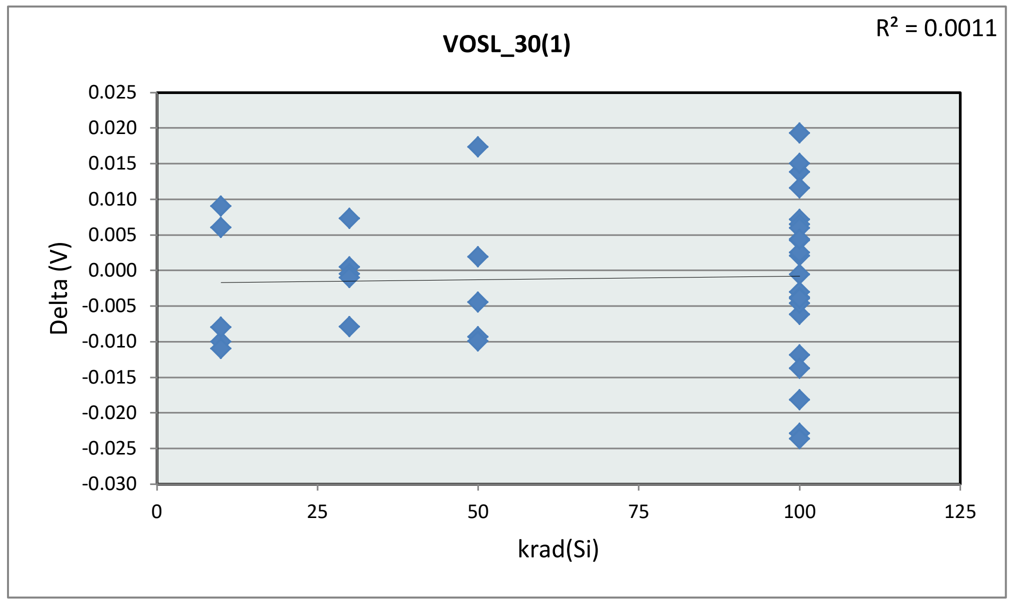


	VOSH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.139	1.120	1.118	1.112
Average	1.142	1.131	1.125	1.129
Max	1.147	1.137	1.134	1.145
UL	1.450	1.450	1.450	1.450

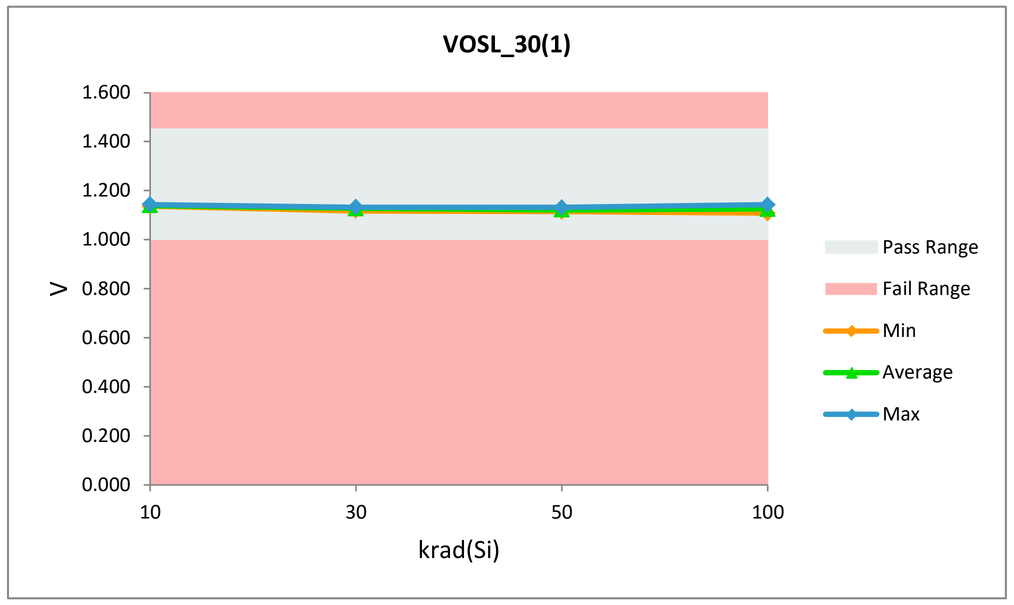


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.126	1.136	-0.010
10	7	1.136	1.144	-0.008
10	8	1.147	1.141	0.006
10	9	1.147	1.138	0.009
10	10	1.125	1.136	-0.011
30	6	1.132	1.132	0.000
30	7	1.117	1.117	0.000
30	8	1.127	1.128	-0.001
30	9	1.134	1.127	0.007
30	10	1.125	1.133	-0.008
50	16	1.123	1.132	-0.009
50	17	1.114	1.124	-0.010
50	18	1.117	1.121	-0.004
50	19	1.116	1.114	0.002
50	20	1.134	1.117	0.017
100	B043	1.121	1.139	-0.018
100	B044	1.128	1.124	0.004
100	B045	1.137	1.123	0.014
100	B046	1.121	1.122	-0.001
100	B047	1.117	1.129	-0.012
100	B048	1.114	1.137	-0.023
100	B049	1.120	1.108	0.012
100	B050	1.119	1.122	-0.003
100	B051	1.125	1.118	0.007
100	B052	1.130	1.115	0.015
100	B053	1.122	1.120	0.002
100	B054	1.113	1.119	-0.006
100	B055	1.120	1.124	-0.004
100	B056	1.132	1.130	0.002
100	B057	1.142	1.123	0.019
100	B058	1.121	1.115	0.006
100	B059	1.127	1.121	0.006
100	B060	1.137	1.133	0.004
100	B061	1.118	1.142	-0.024
100	B062	1.118	1.123	-0.005
100	B063	1.122	1.126	-0.004
100	B064	1.123	1.137	-0.014
	Max	1.147	1.144	0.019
	Average	1.126	1.127	-0.001
	Min	1.113	1.108	-0.024
	Std Dev	0.009	0.009	0.010

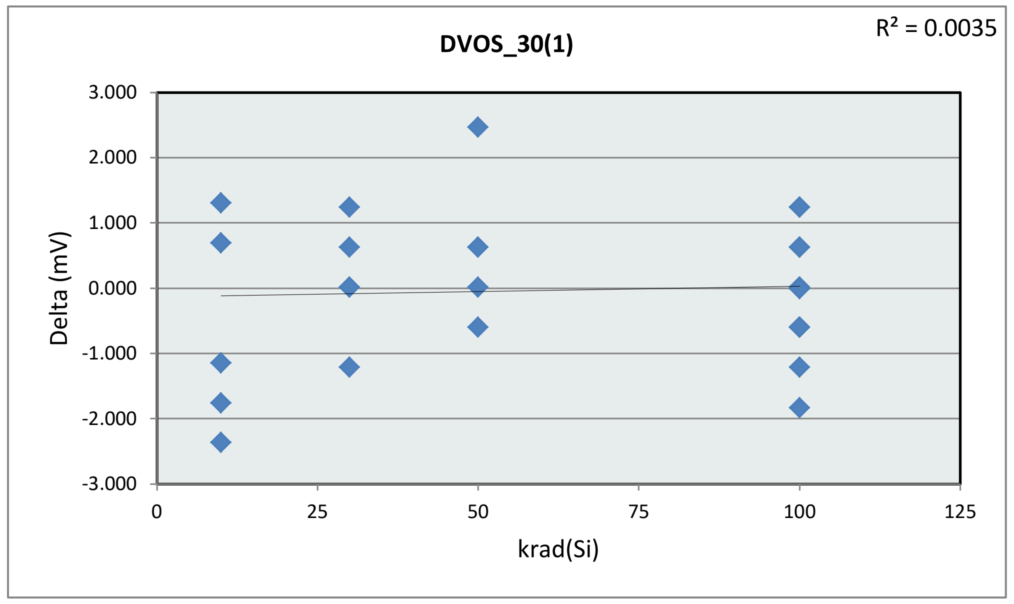


	VOSL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.136	1.117	1.114	1.108
Average	1.139	1.127	1.122	1.125
Max	1.144	1.133	1.132	1.142
UL	1.450	1.450	1.450	1.450

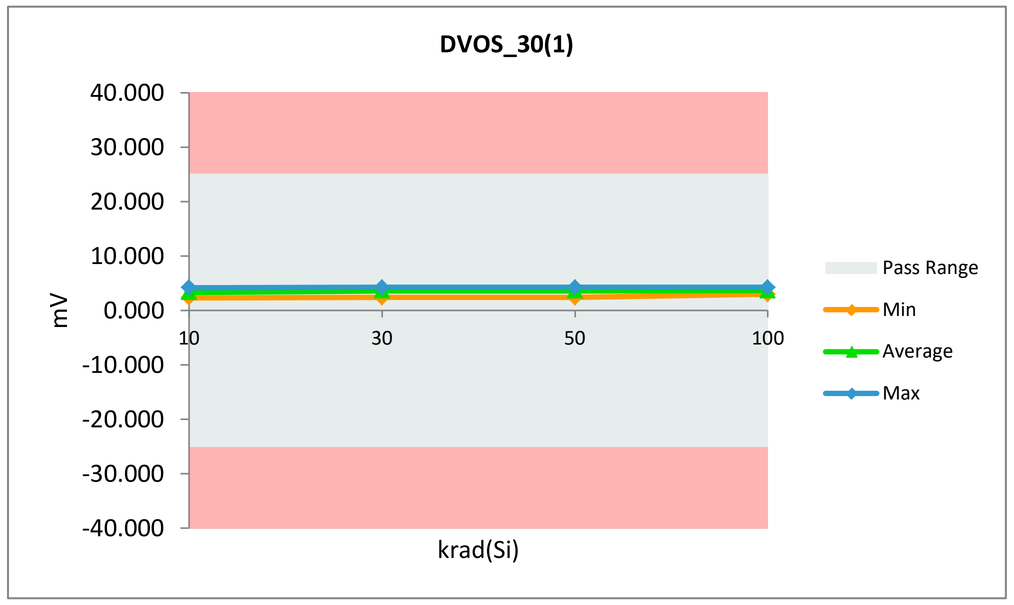


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOS_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	2.437	3.581	-1.144
10	7	3.664	2.360	1.304
10	8	1.823	3.580	-1.757
10	9	1.823	4.191	-2.368
10	10	3.663	2.969	0.694
30	6	3.025	2.400	0.625
30	7	3.638	3.626	0.012
30	8	5.480	4.242	1.238
30	9	3.026	4.241	-1.215
30	10	3.638	3.628	0.010
50	16	4.867	2.400	2.467
50	17	4.252	3.627	0.625
50	18	3.638	4.241	-0.603
50	19	4.253	4.240	0.013
50	20	4.252	3.626	0.626
100	B043	3.025	3.628	-0.603
100	B044	4.253	3.628	0.625
100	B045	3.640	3.628	0.012
100	B046	3.639	3.013	0.626
100	B047	4.867	3.627	1.240
100	B048	3.639	3.628	0.011
100	B049	3.638	4.240	-0.602
100	B050	3.638	3.014	0.624
100	B051	3.639	4.242	-0.603
100	B052	3.025	4.240	-1.215
100	B053	3.640	3.627	0.013
100	B054	3.638	3.627	0.011
100	B055	3.639	4.240	-0.601
100	B056	2.411	4.241	-1.830
100	B057	3.026	3.628	-0.602
100	B058	3.025	3.627	-0.602
100	B059	3.026	3.014	0.012
100	B060	4.253	3.014	1.239
100	B061	4.251	3.014	1.237
100	B062	4.252	4.259	-0.007
100	B063	3.639	4.242	-0.603
100	B064	4.253	3.628	0.625
	Max	5.480	4.259	2.467
	Average	3.609	3.622	-0.013
	Min	1.823	2.360	-2.368
	Std Dev	0.774	0.563	1.005

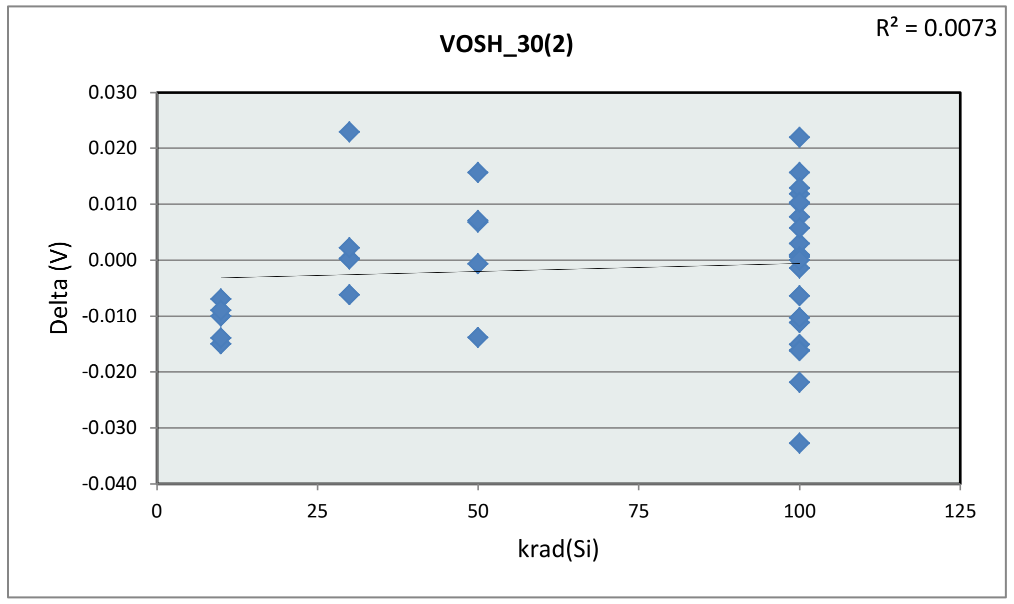


	DVOS_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.360	2.400	2.400	3.013
Average	3.336	3.627	3.627	3.684
Max	4.191	4.242	4.241	4.259
UL	25.000	25.000	25.000	25.000

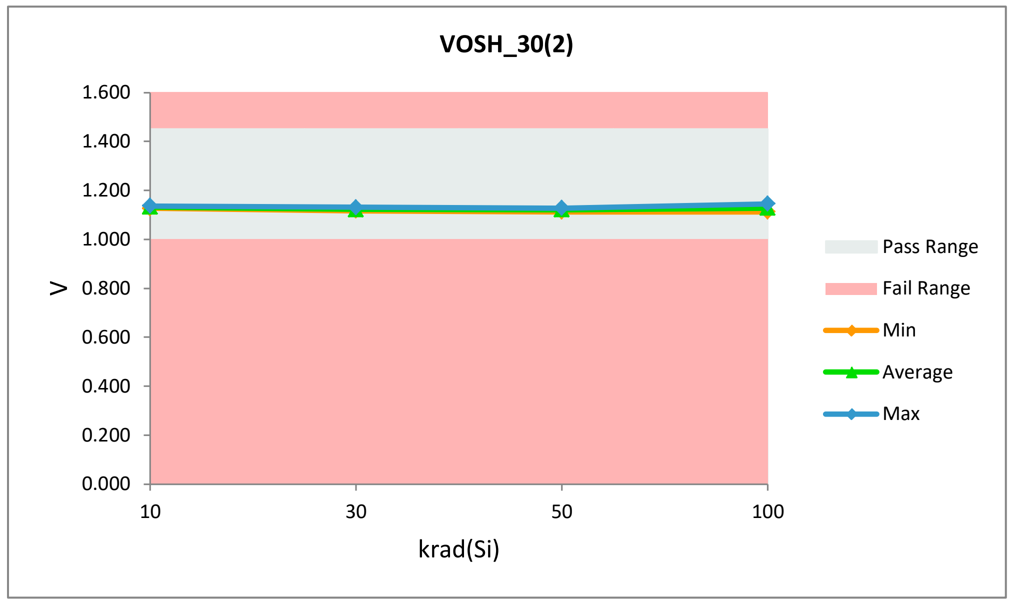


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.118	1.128	-0.010
10	7	1.121	1.136	-0.015
10	8	1.124	1.131	-0.007
10	9	1.127	1.136	-0.009
10	10	1.113	1.127	-0.014
30	6	1.131	1.131	0.000
30	7	1.117	1.117	0.000
30	8	1.125	1.123	0.002
30	9	1.118	1.124	-0.006
30	10	1.140	1.117	0.023
50	16	1.126	1.119	0.007
50	17	1.128	1.112	0.016
50	18	1.123	1.124	-0.001
50	19	1.114	1.128	-0.014
50	20	1.130	1.123	0.007
100	B043	1.121	1.136	-0.015
100	B044	1.132	1.131	0.001
100	B045	1.141	1.131	0.010
100	B046	1.143	1.121	0.022
100	B047	1.145	1.133	0.012
100	B048	1.129	1.140	-0.011
100	B049	1.115	1.114	0.001
100	B050	1.136	1.142	-0.006
100	B051	1.112	1.145	-0.033
100	B052	1.120	1.130	-0.010
100	B053	1.123	1.115	0.008
100	B054	1.114	1.136	-0.022
100	B055	1.128	1.112	0.016
100	B056	1.124	1.121	0.003
100	B057	1.137	1.124	0.013
100	B058	1.113	1.115	-0.002
100	B059	1.139	1.129	0.010
100	B060	1.125	1.124	0.001
100	B061	1.121	1.137	-0.016
100	B062	1.116	1.116	0.000
100	B063	1.123	1.139	-0.016
100	B064	1.131	1.125	0.006
	Max	1.145	1.145	0.023
	Average	1.125	1.127	-0.001
	Min	1.112	1.112	-0.033
	Std Dev	0.009	0.009	0.012



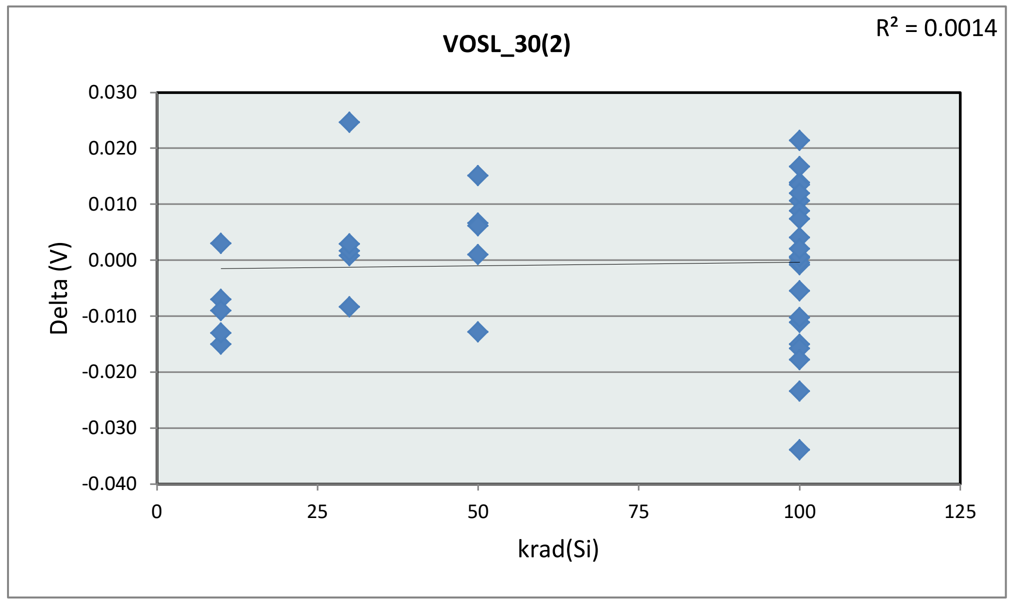
	VOSH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.127	1.117	1.112	1.112
Average	1.132	1.122	1.121	1.128
Max	1.136	1.131	1.128	1.145
UL	1.450	1.450	1.450	1.450



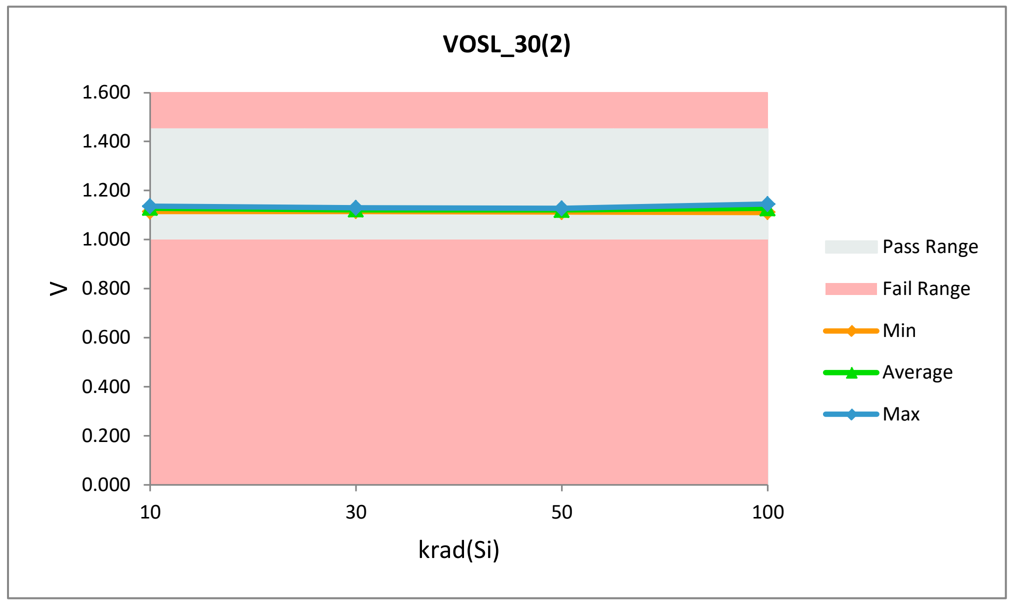
HDR UnBiased TID Report
SN55LVCP22A-SP

	VOSL_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.117	1.114	0.003
10	7	1.121	1.136	-0.015
10	8	1.124	1.131	-0.007
10	9	1.127	1.136	-0.009
10	10	1.113	1.126	-0.013
30	6	1.131	1.130	0.001
30	7	1.117	1.115	0.002
30	8	1.126	1.123	0.003
30	9	1.117	1.125	-0.008
30	10	1.141	1.116	0.025
50	16	1.125	1.118	0.007
50	17	1.127	1.112	0.015
50	18	1.124	1.123	0.001
50	19	1.114	1.127	-0.013
50	20	1.130	1.124	0.006
100	B043	1.121	1.136	-0.015
100	B044	1.131	1.131	0.000
100	B045	1.141	1.130	0.011
100	B046	1.142	1.121	0.021
100	B047	1.145	1.131	0.014
100	B048	1.129	1.140	-0.011
100	B049	1.114	1.115	-0.001
100	B050	1.138	1.143	-0.005
100	B051	1.111	1.145	-0.034
100	B052	1.120	1.130	-0.010
100	B053	1.123	1.114	0.009
100	B054	1.114	1.137	-0.023
100	B055	1.128	1.111	0.017
100	B056	1.124	1.120	0.004
100	B057	1.138	1.124	0.014
100	B058	1.114	1.114	0.000
100	B059	1.140	1.128	0.012
100	B060	1.125	1.124	0.001
100	B061	1.122	1.138	-0.016
100	B062	1.116	1.114	0.002
100	B063	1.122	1.140	-0.018
100	B064	1.131	1.124	0.007
	Max	1.145	1.145	0.025
	Average	1.125	1.126	-0.001
	Min	1.111	1.111	-0.034
	Std Dev	0.009	0.009	0.013

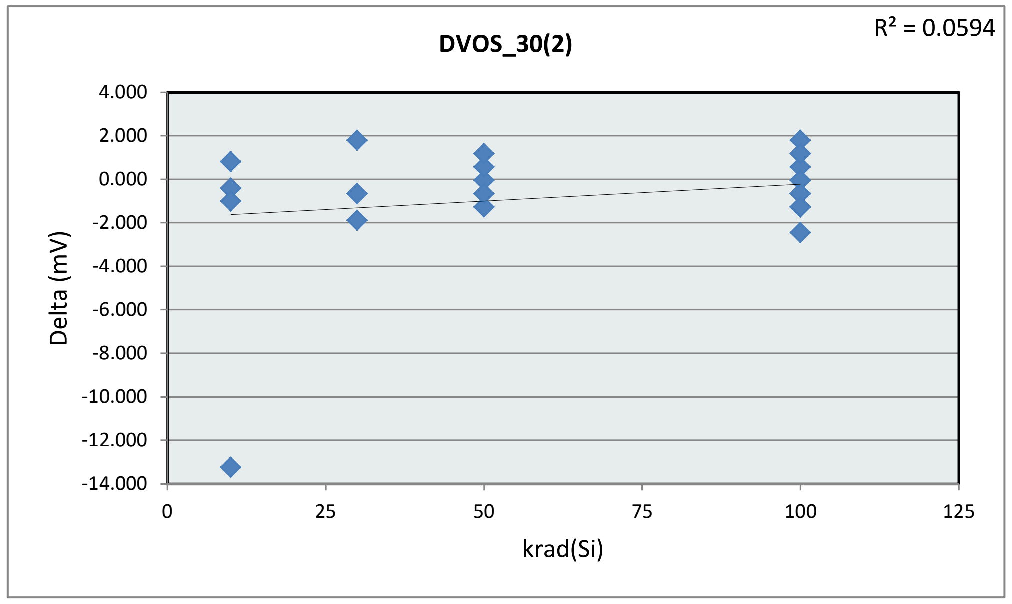


	VOSL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.114	1.115	1.112	1.111
Average	1.129	1.122	1.121	1.128
Max	1.136	1.130	1.127	1.145
UL	1.450	1.450	1.450	1.450

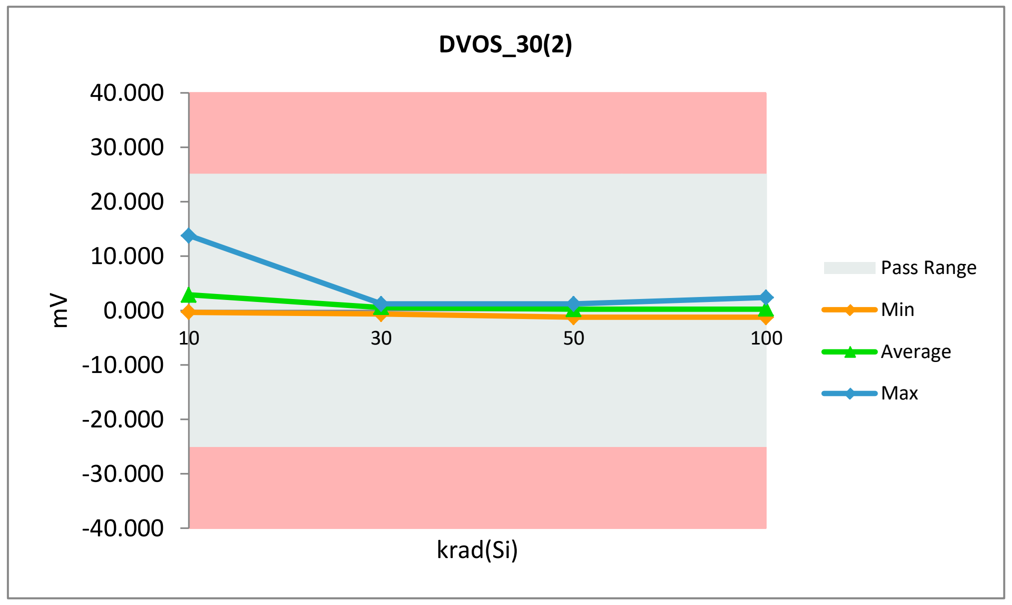


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOS_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	0.523	13.770	-13.247
10	7	-0.092	0.327	-0.418
10	8	0.524	-0.289	0.813
10	9	-0.092	0.324	-0.415
10	10	-0.706	0.319	-1.025
30	6	0.551	1.225	-0.674
30	7	0.550	1.225	-0.675
30	8	-0.676	-0.002	-0.673
30	9	1.164	-0.616	1.781
30	10	-0.678	1.225	-1.903
50	16	1.164	1.225	-0.061
50	17	0.550	-0.003	0.553
50	18	-0.677	0.611	-1.288
50	19	-0.063	0.611	-0.674
50	20	-0.063	-1.230	1.167
100	B043	-0.063	0.611	-0.674
100	B044	0.551	0.611	-0.060
100	B045	0.552	1.225	-0.673
100	B046	0.551	-0.002	0.553
100	B047	-0.063	1.225	-1.288
100	B048	-0.063	-0.002	-0.061
100	B049	0.550	-0.616	1.166
100	B050	-1.905	-0.616	-1.289
100	B051	1.164	-0.002	1.167
100	B052	-0.063	-0.002	-0.060
100	B053	-0.061	0.611	-0.672
100	B054	0.550	-1.230	1.780
100	B055	-0.063	1.225	-1.288
100	B056	-0.062	0.611	-0.674
100	B057	-0.675	-0.002	-0.673
100	B058	-0.062	0.611	-0.673
100	B059	-0.676	0.611	-1.287
100	B060	-0.063	-0.002	-0.060
100	B061	-1.292	-0.616	-0.676
100	B062	-0.063	2.395	-2.458
100	B063	0.551	-0.616	1.167
100	B064	-0.676	0.611	-1.287
	Max	1.164	13.770	1.781
	Average	0.016	0.685	-0.669
	Min	-1.905	-1.230	-13.247
	Std Dev	0.665	2.340	2.345



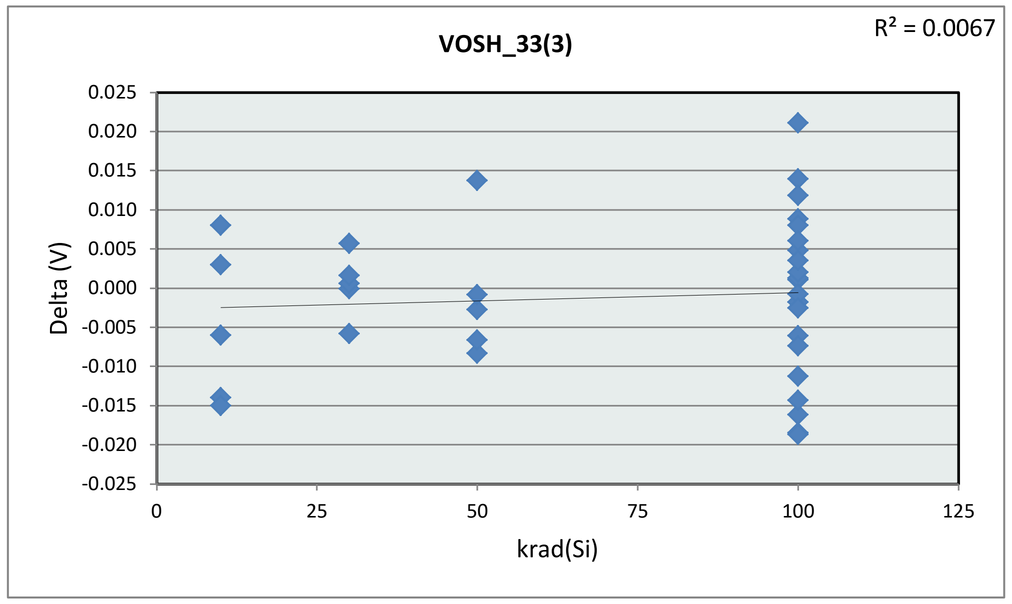
	DVOS_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.289	-0.616	-1.230	-1.230
Average	2.890	0.611	0.243	0.302
Max	13.770	1.225	1.225	2.395
UL	25.000	25.000	25.000	25.000



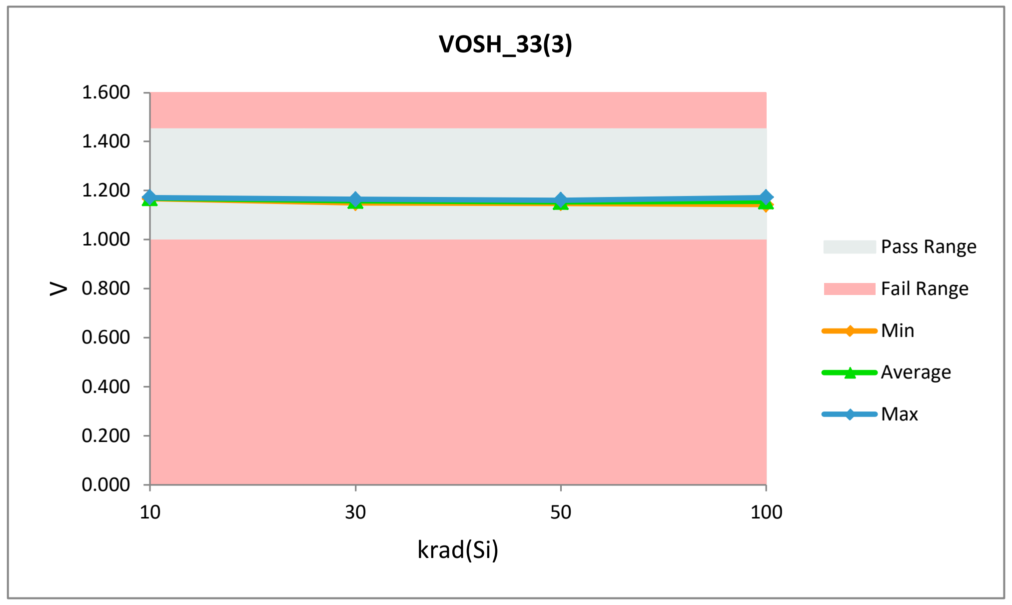
HDR UnBiased TID Report
SN55LVCP22A-SP

	VOSH_33(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.152	1.166	-0.014
10	7	1.166	1.172	-0.006
10	8	1.173	1.170	0.003
10	9	1.177	1.169	0.008
10	10	1.153	1.168	-0.015
30	6	1.162	1.162	0.000
30	7	1.150	1.149	0.001
30	8	1.158	1.156	0.002
30	9	1.164	1.158	0.006
30	10	1.158	1.164	-0.006
50	16	1.153	1.161	-0.008
50	17	1.148	1.155	-0.007
50	18	1.150	1.153	-0.003
50	19	1.147	1.148	-0.001
50	20	1.164	1.150	0.014
100	B043	1.151	1.167	-0.016
100	B044	1.159	1.154	0.005
100	B045	1.165	1.151	0.014
100	B046	1.150	1.152	-0.002
100	B047	1.148	1.159	-0.011
100	B048	1.147	1.165	-0.018
100	B049	1.151	1.142	0.009
100	B050	1.152	1.151	0.001
100	B051	1.157	1.149	0.008
100	B052	1.159	1.147	0.012
100	B053	1.150	1.152	-0.002
100	B054	1.146	1.152	-0.006
100	B055	1.150	1.157	-0.007
100	B056	1.161	1.160	0.001
100	B057	1.171	1.150	0.021
100	B058	1.149	1.147	0.002
100	B059	1.155	1.151	0.004
100	B060	1.168	1.162	0.006
100	B061	1.153	1.172	-0.019
100	B062	1.150	1.151	-0.001
100	B063	1.151	1.154	-0.003
100	B064	1.153	1.167	-0.014
	Max	1.177	1.172	0.021
	Average	1.156	1.157	-0.001
	Min	1.146	1.142	-0.019
	Std Dev	0.008	0.008	0.009



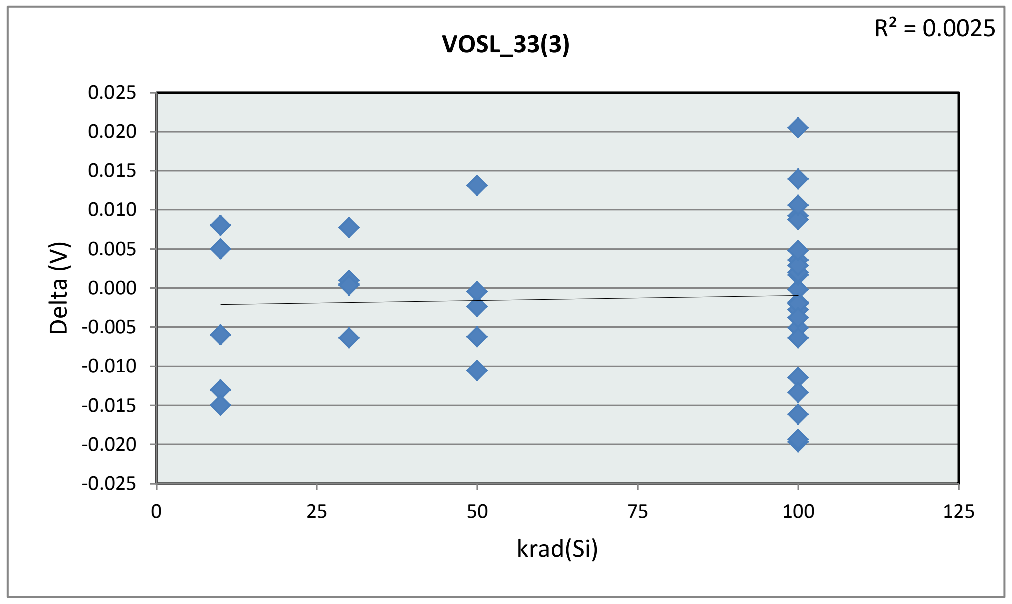
	VOSH_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.166	1.149	1.148	1.142
Average	1.169	1.158	1.153	1.155
Max	1.172	1.164	1.161	1.172
UL	1.450	1.450	1.450	1.450



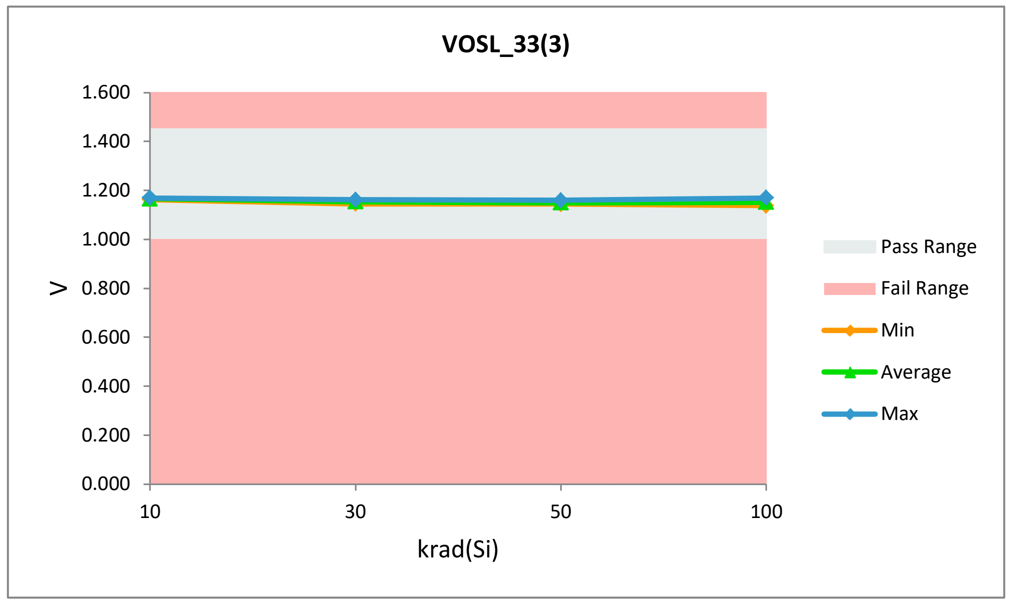
HDR UnBiased TID Report
SN55LVCP22A-SP

	VOSL_33(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.150	1.163	-0.013
10	7	1.163	1.169	-0.006
10	8	1.171	1.166	0.005
10	9	1.174	1.166	0.008
10	10	1.150	1.165	-0.015
30	6	1.159	1.159	0.000
30	7	1.146	1.145	0.001
30	8	1.153	1.153	0.000
30	9	1.161	1.153	0.008
30	10	1.155	1.161	-0.006
50	16	1.148	1.159	-0.011
50	17	1.145	1.151	-0.006
50	18	1.147	1.149	-0.002
50	19	1.144	1.144	0.000
50	20	1.160	1.147	0.013
100	B043	1.148	1.164	-0.016
100	B044	1.155	1.151	0.004
100	B045	1.162	1.148	0.014
100	B046	1.147	1.149	-0.002
100	B047	1.144	1.155	-0.011
100	B048	1.142	1.162	-0.020
100	B049	1.147	1.138	0.009
100	B050	1.148	1.148	0.000
100	B051	1.153	1.144	0.009
100	B052	1.155	1.144	0.011
100	B053	1.147	1.150	-0.003
100	B054	1.143	1.148	-0.005
100	B055	1.147	1.153	-0.006
100	B056	1.158	1.156	0.002
100	B057	1.167	1.147	0.020
100	B058	1.146	1.144	0.002
100	B059	1.151	1.148	0.003
100	B060	1.164	1.159	0.005
100	B061	1.150	1.169	-0.019
100	B062	1.146	1.148	-0.002
100	B063	1.147	1.151	-0.004
100	B064	1.150	1.163	-0.013
	Max	1.174	1.169	0.020
	Average	1.152	1.154	-0.001
	Min	1.142	1.138	-0.020
	Std Dev	0.008	0.008	0.010



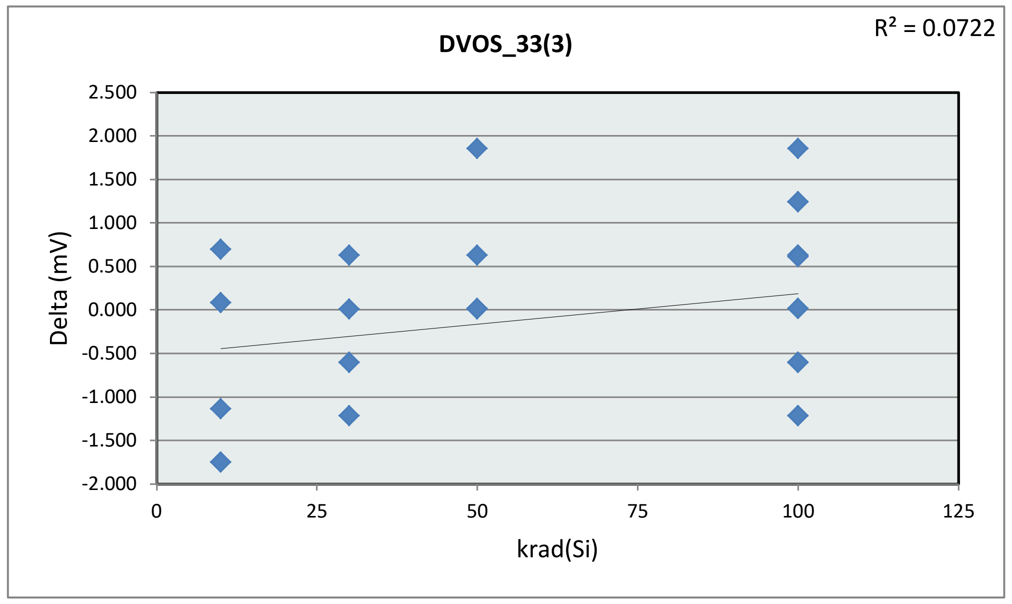
	VOSL_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.163	1.145	1.144	1.138
Average	1.166	1.154	1.150	1.152
Max	1.169	1.161	1.159	1.169
UL	1.450	1.450	1.450	1.450



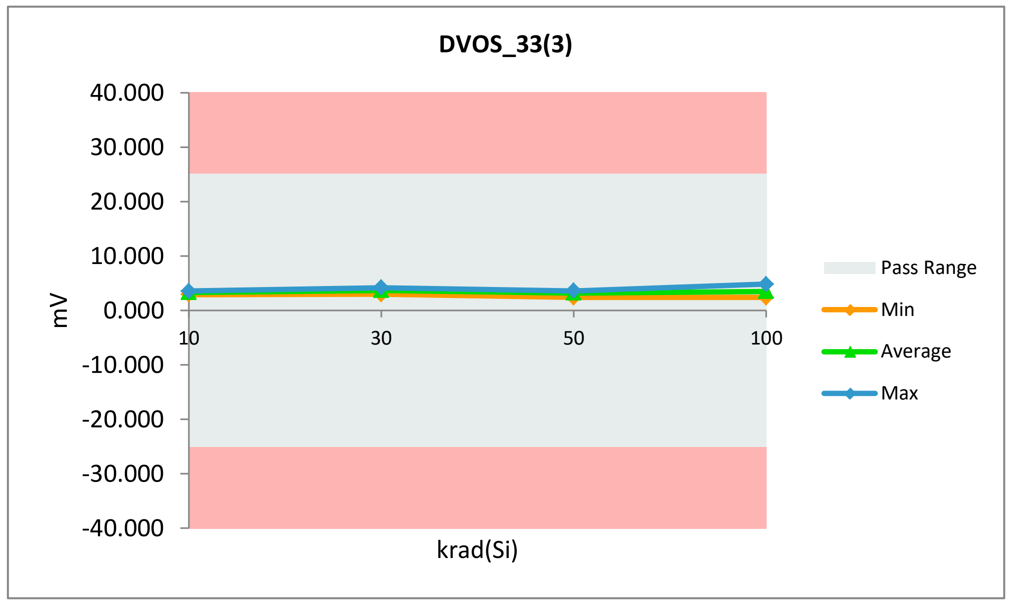
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVOS_33(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.822	3.575	-1.753
10	7	3.049	2.964	0.085
10	8	1.822	3.574	-1.752
10	9	2.435	3.575	-1.140
10	10	3.662	2.965	0.697
30	6	2.409	3.010	-0.601
30	7	3.637	4.238	-0.601
30	8	4.250	3.624	0.626
30	9	3.023	4.238	-1.215
30	10	3.636	3.624	0.012
50	16	4.251	2.397	1.854
50	17	3.636	3.624	0.012
50	18	3.636	3.625	0.011
50	19	3.636	3.624	0.012
50	20	3.636	3.010	0.626
100	B043	3.022	3.624	-0.602
100	B044	4.250	3.011	1.239
100	B045	3.022	3.625	-0.603
100	B046	3.023	3.011	0.012
100	B047	4.250	4.238	0.012
100	B048	4.250	3.010	1.240
100	B049	3.637	4.238	-0.601
100	B050	4.250	3.011	1.239
100	B051	4.250	4.851	-0.601
100	B052	4.250	3.624	0.626
100	B053	3.023	2.397	0.626
100	B054	3.023	4.238	-1.215
100	B055	3.023	4.237	-1.214
100	B056	3.636	4.238	-0.602
100	B057	3.636	3.624	0.012
100	B058	3.023	3.624	-0.601
100	B059	3.637	3.011	0.626
100	B060	4.250	2.397	1.853
100	B061	3.636	3.011	0.625
100	B062	4.250	3.643	0.607
100	B063	4.250	3.011	1.239
100	B064	3.022	4.238	-1.216
	Max	4.251	4.851	1.854
	Average	3.491	3.502	-0.012
	Min	1.822	2.397	-1.753
	Std Dev	0.680	0.595	0.950

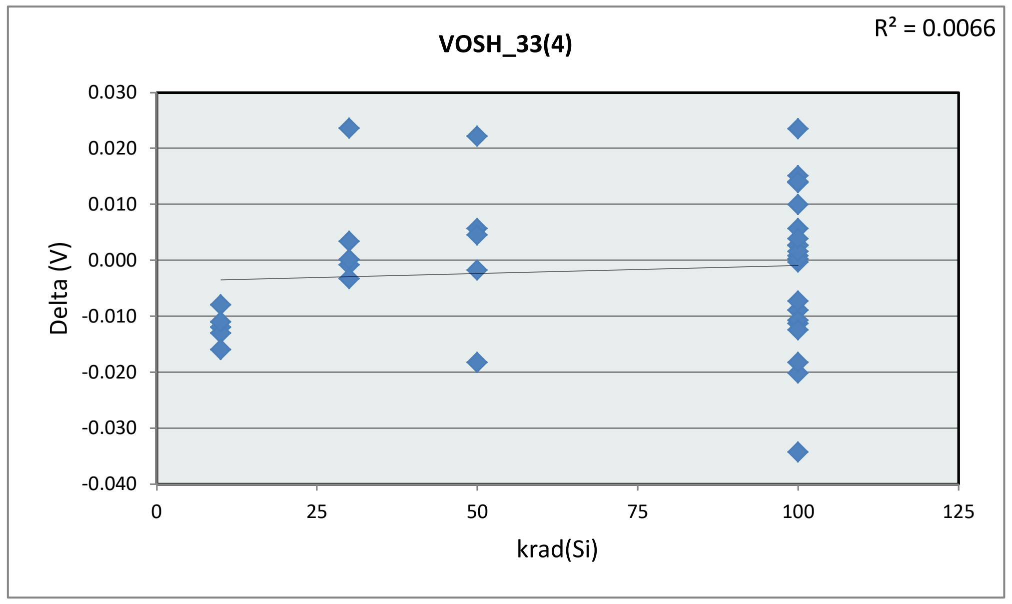


	DVOS_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.964	3.010	2.397	2.397
Average	3.331	3.747	3.256	3.541
Max	3.575	4.238	3.625	4.851
UL	25.000	25.000	25.000	25.000

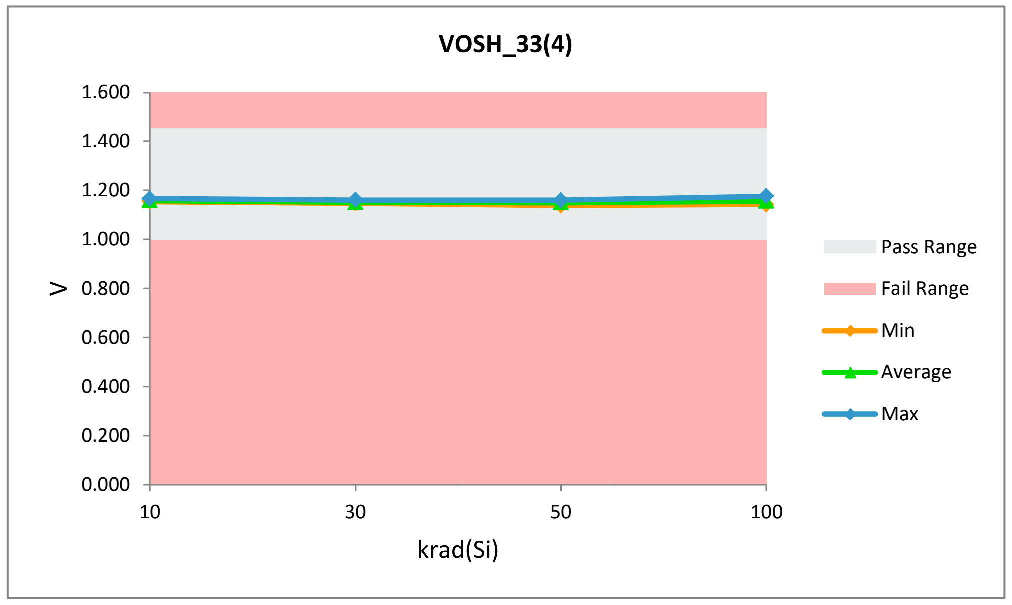


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSH_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.143	1.155	-0.012
10	7	1.148	1.161	-0.013
10	8	1.149	1.157	-0.008
10	9	1.155	1.166	-0.011
10	10	1.141	1.157	-0.016
30	6	1.160	1.161	-0.001
30	7	1.149	1.149	0.000
30	8	1.150	1.147	0.003
30	9	1.147	1.150	-0.003
30	10	1.171	1.147	0.024
50	16	1.155	1.149	0.006
50	17	1.160	1.138	0.022
50	18	1.152	1.154	-0.002
50	19	1.142	1.160	-0.018
50	20	1.156	1.152	0.004
100	B043	1.150	1.161	-0.011
100	B044	1.161	1.160	0.001
100	B045	1.167	1.157	0.010
100	B046	1.172	1.149	0.023
100	B047	1.175	1.161	0.014
100	B048	1.157	1.166	-0.009
100	B049	1.147	1.144	0.003
100	B050	1.165	1.174	-0.009
100	B051	1.142	1.176	-0.034
100	B052	1.147	1.158	-0.011
100	B053	1.147	1.147	0.000
100	B054	1.145	1.165	-0.020
100	B055	1.157	1.142	0.015
100	B056	1.152	1.149	0.003
100	B057	1.162	1.148	0.014
100	B058	1.139	1.146	-0.007
100	B059	1.166	1.160	0.006
100	B060	1.152	1.152	0.000
100	B061	1.152	1.164	-0.012
100	B062	1.144	1.142	0.002
100	B063	1.150	1.168	-0.018
100	B064	1.156	1.152	0.004
	Max	1.175	1.176	0.024
	Average	1.154	1.155	-0.002
	Min	1.139	1.138	-0.034
	Std Dev	0.009	0.009	0.013

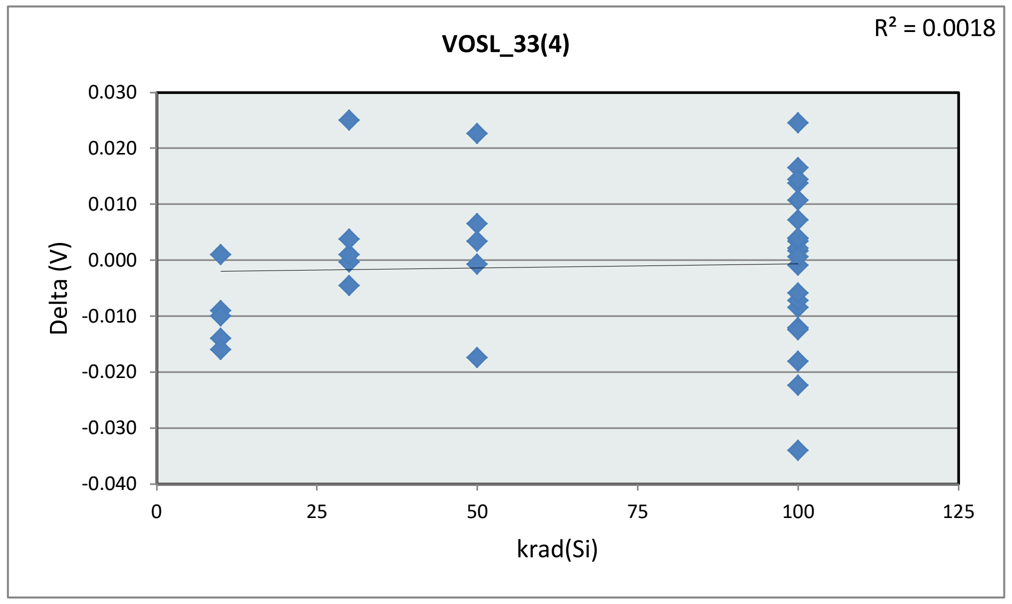


	VOSH_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.155	1.147	1.138	1.142
Average	1.159	1.151	1.151	1.156
Max	1.166	1.161	1.160	1.176
UL	1.450	1.450	1.450	1.450

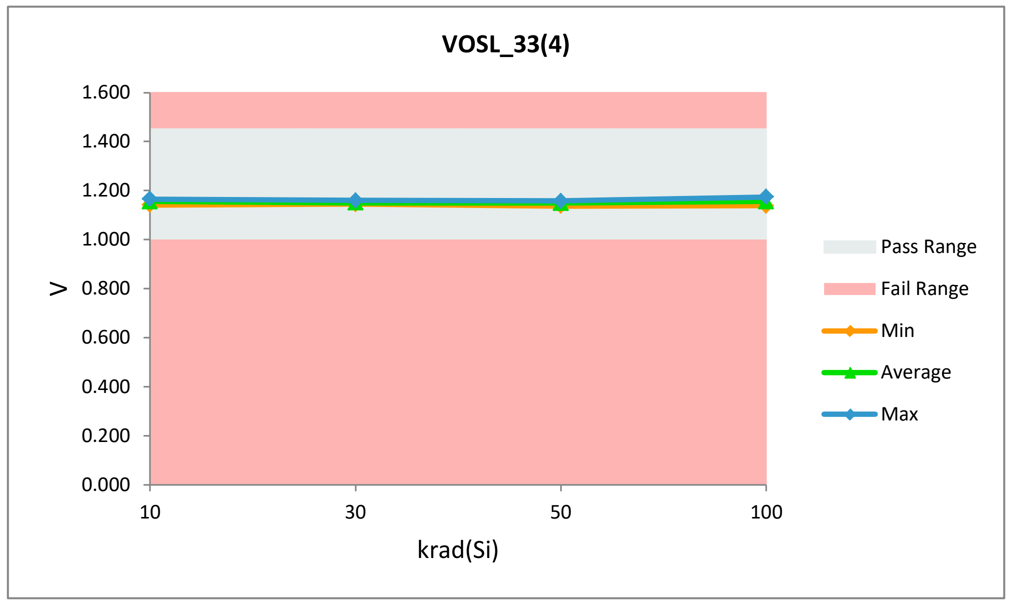


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSL_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.142	1.141	0.001
10	7	1.147	1.161	-0.014
10	8	1.147	1.156	-0.009
10	9	1.155	1.165	-0.010
10	10	1.140	1.156	-0.016
30	6	1.160	1.160	0.000
30	7	1.148	1.147	0.001
30	8	1.150	1.146	0.004
30	9	1.145	1.150	-0.005
30	10	1.170	1.145	0.025
50	16	1.153	1.147	0.006
50	17	1.160	1.137	0.023
50	18	1.152	1.153	-0.001
50	19	1.141	1.158	-0.017
50	20	1.155	1.152	0.003
100	B043	1.148	1.160	-0.012
100	B044	1.160	1.158	0.002
100	B045	1.166	1.155	0.011
100	B046	1.173	1.148	0.025
100	B047	1.174	1.160	0.014
100	B048	1.157	1.165	-0.008
100	B049	1.146	1.144	0.002
100	B050	1.166	1.173	-0.007
100	B051	1.140	1.174	-0.034
100	B052	1.145	1.158	-0.013
100	B053	1.146	1.147	-0.001
100	B054	1.144	1.166	-0.022
100	B055	1.157	1.140	0.017
100	B056	1.150	1.147	0.003
100	B057	1.161	1.147	0.014
100	B058	1.138	1.144	-0.006
100	B059	1.165	1.158	0.007
100	B060	1.152	1.151	0.001
100	B061	1.152	1.164	-0.012
100	B062	1.142	1.138	0.004
100	B063	1.148	1.166	-0.018
100	B064	1.156	1.152	0.004
	Max	1.174	1.174	0.025
	Average	1.153	1.154	-0.001
	Min	1.138	1.137	-0.034
	Std Dev	0.009	0.009	0.013

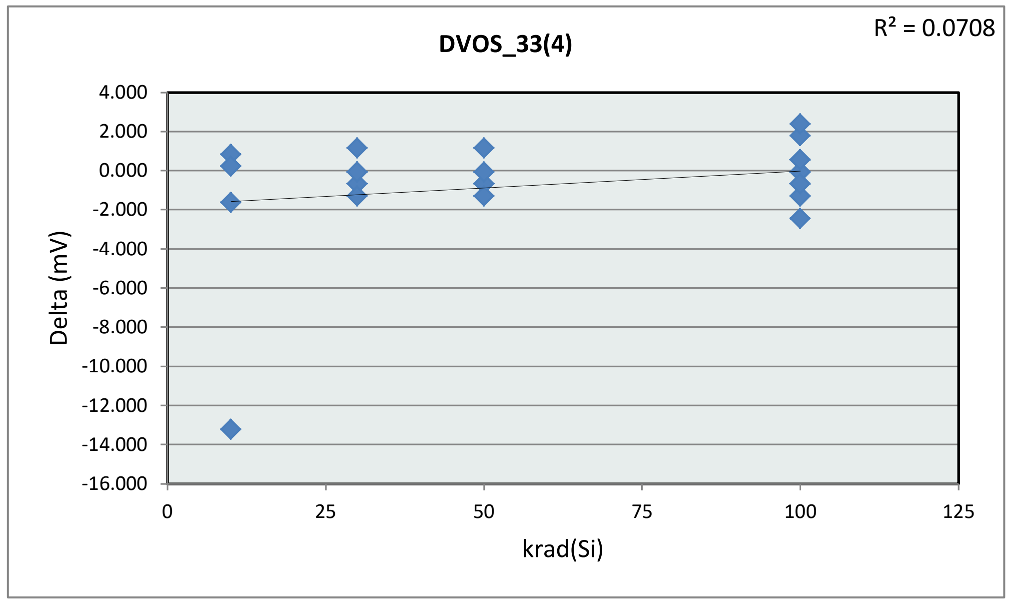


	VOSL_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.141	1.145	1.137	1.138
Average	1.156	1.150	1.149	1.155
Max	1.165	1.160	1.158	1.174
UL	1.450	1.450	1.450	1.450

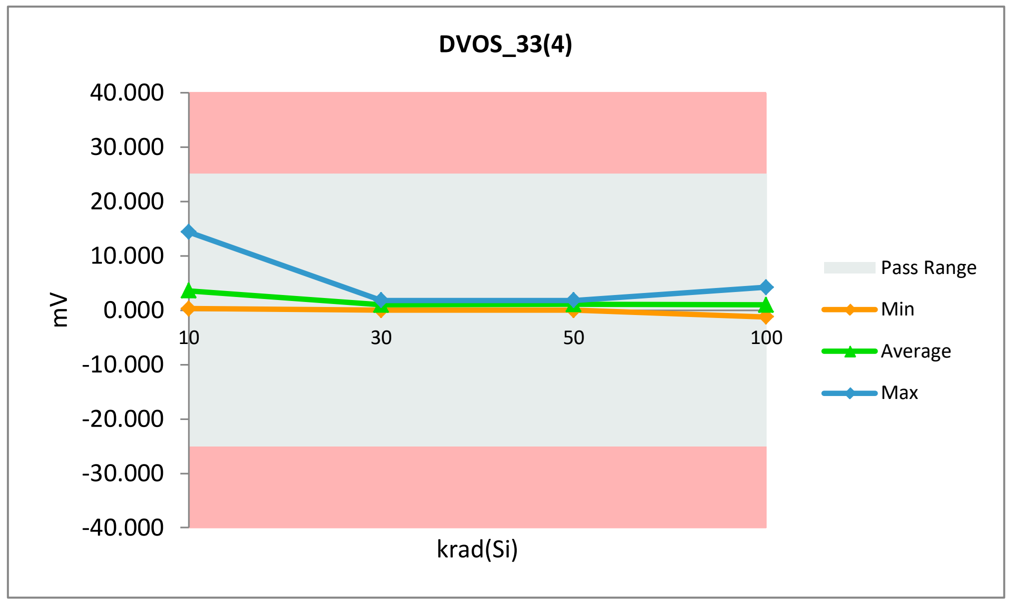


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOS_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.130	14.364	-13.234
10	7	0.515	0.301	0.214
10	8	1.743	0.913	0.830
10	9	-0.098	1.529	-1.627
10	10	1.129	0.915	0.214
30	6	0.547	1.225	-0.678
30	7	1.161	1.225	-0.064
30	8	0.547	0.611	-0.064
30	9	1.161	-0.003	1.163
30	10	0.546	1.838	-1.292
50	16	1.161	1.838	-0.677
50	17	0.546	1.225	-0.679
50	18	-0.067	1.225	-1.292
50	19	1.161	1.225	-0.064
50	20	1.160	-0.003	1.163
100	B043	1.774	1.225	0.549
100	B044	1.161	1.225	-0.064
100	B045	1.161	1.225	-0.064
100	B046	-0.067	0.611	-0.678
100	B047	1.160	1.225	-0.065
100	B048	0.547	1.225	-0.678
100	B049	0.547	0.611	-0.064
100	B050	-0.681	0.611	-1.292
100	B051	1.775	1.225	0.550
100	B052	1.775	-0.003	1.777
100	B053	0.547	-0.003	0.549
100	B054	1.161	-1.230	2.391
100	B055	0.546	1.838	-1.292
100	B056	1.161	1.225	-0.064
100	B057	0.547	0.611	-0.064
100	B058	0.547	1.838	-1.291
100	B059	0.546	1.225	-0.679
100	B060	0.547	0.611	-0.064
100	B061	-0.068	-0.003	-0.065
100	B062	1.774	4.231	-2.457
100	B063	1.775	1.225	0.550
100	B064	-0.067	0.611	-0.678
	Max	1.775	14.364	2.391
	Average	0.825	1.346	-0.521
	Min	-0.681	-1.230	-13.234
	Std Dev	0.623	2.357	2.351

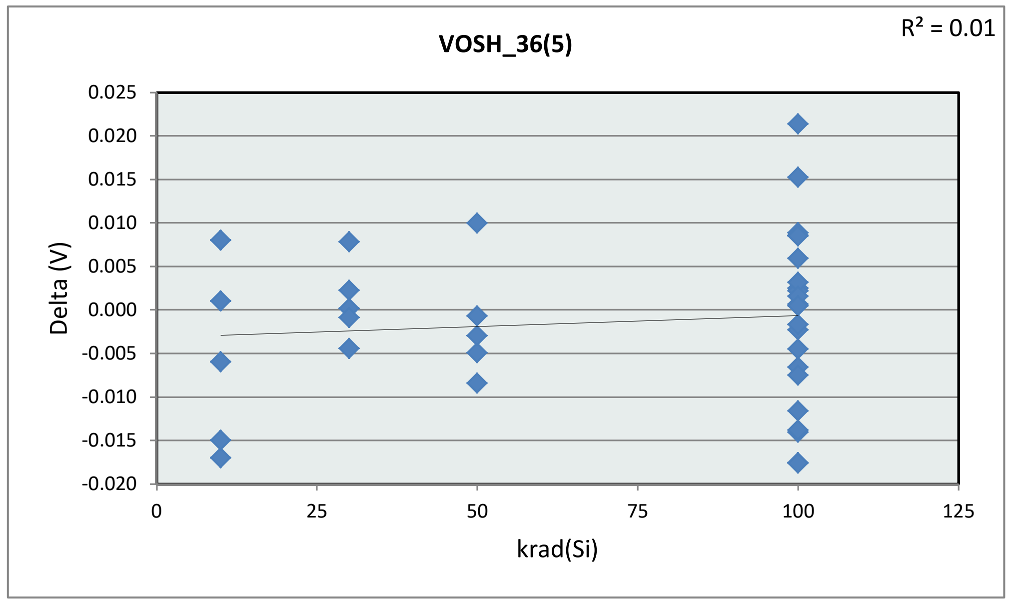


	DVOS_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.301	-0.003	-0.003	-1.230
Average	3.604	0.979	1.102	0.971
Max	14.364	1.838	1.838	4.231
UL	25.000	25.000	25.000	25.000

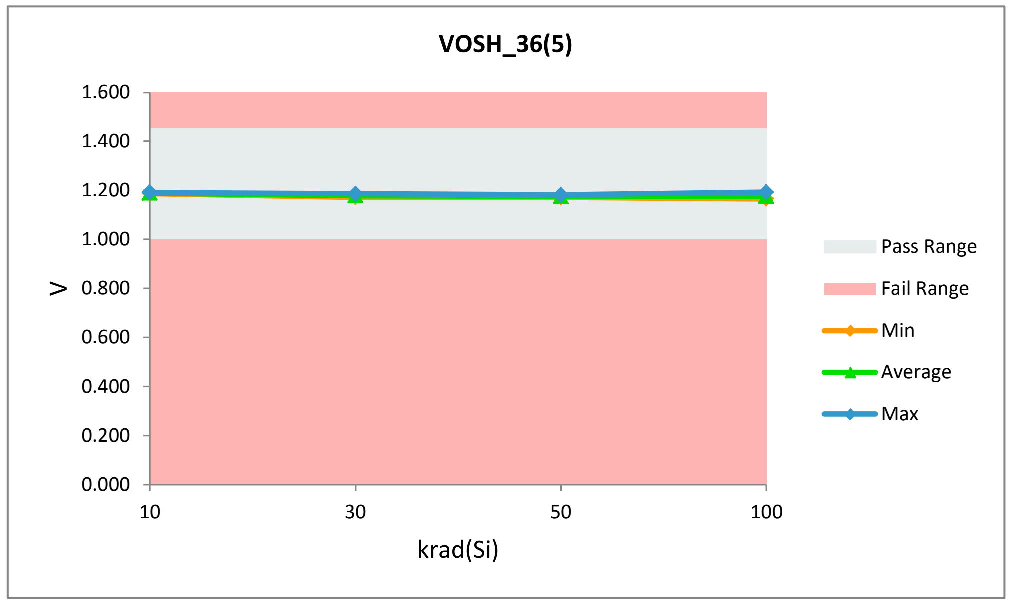


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSH_36(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.170	1.187	-0.017
10	7	1.186	1.192	-0.006
10	8	1.190	1.189	0.001
10	9	1.198	1.190	0.008
10	10	1.174	1.189	-0.015
30	6	1.182	1.182	0.000
30	7	1.171	1.172	-0.001
30	8	1.177	1.175	0.002
30	9	1.186	1.178	0.008
30	10	1.182	1.186	-0.004
50	16	1.174	1.182	-0.008
50	17	1.171	1.176	-0.005
50	18	1.172	1.173	-0.001
50	19	1.168	1.171	-0.003
50	20	1.184	1.174	0.010
100	B043	1.173	1.187	-0.014
100	B044	1.178	1.176	0.002
100	B045	1.185	1.170	0.015
100	B046	1.172	1.174	-0.002
100	B047	1.167	1.179	-0.012
100	B048	1.167	1.185	-0.018
100	B049	1.174	1.165	0.009
100	B050	1.174	1.172	0.002
100	B051	1.178	1.169	0.009
100	B052	1.178	1.170	0.008
100	B053	1.170	1.175	-0.005
100	B054	1.167	1.174	-0.007
100	B055	1.170	1.178	-0.008
100	B056	1.182	1.179	0.003
100	B057	1.191	1.170	0.021
100	B058	1.169	1.168	0.001
100	B059	1.174	1.172	0.002
100	B060	1.189	1.183	0.006
100	B061	1.175	1.193	-0.018
100	B062	1.170	1.170	0.000
100	B063	1.172	1.174	-0.002
100	B064	1.174	1.188	-0.014
	Max	1.198	1.193	0.021
	Average	1.177	1.178	-0.001
	Min	1.167	1.165	-0.018
	Std Dev	0.008	0.008	0.009



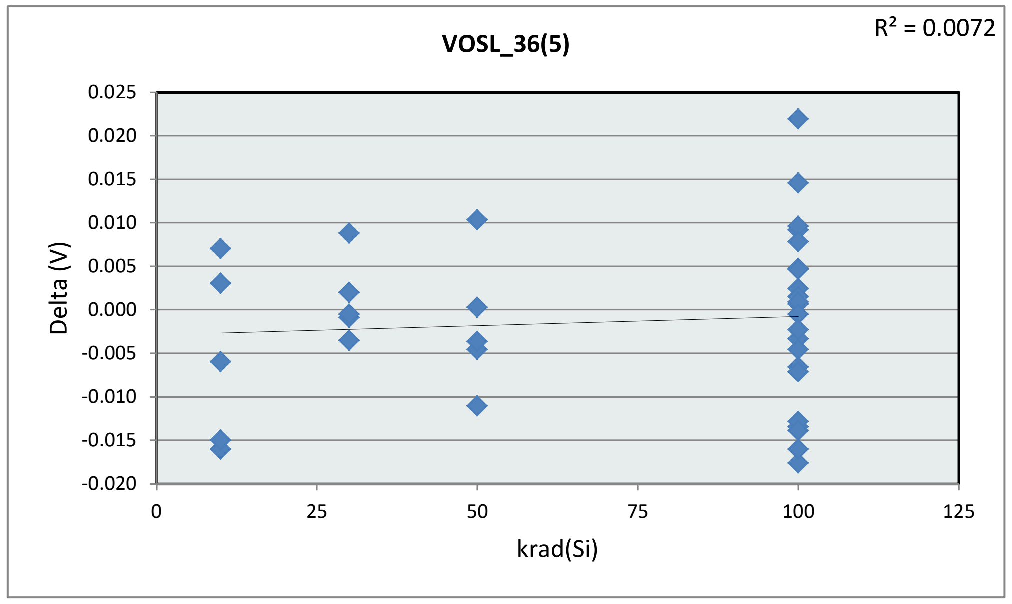
	VOSH_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.187	1.172	1.171	1.165
Average	1.189	1.179	1.175	1.176
Max	1.192	1.186	1.182	1.193
UL	1.450	1.450	1.450	1.450



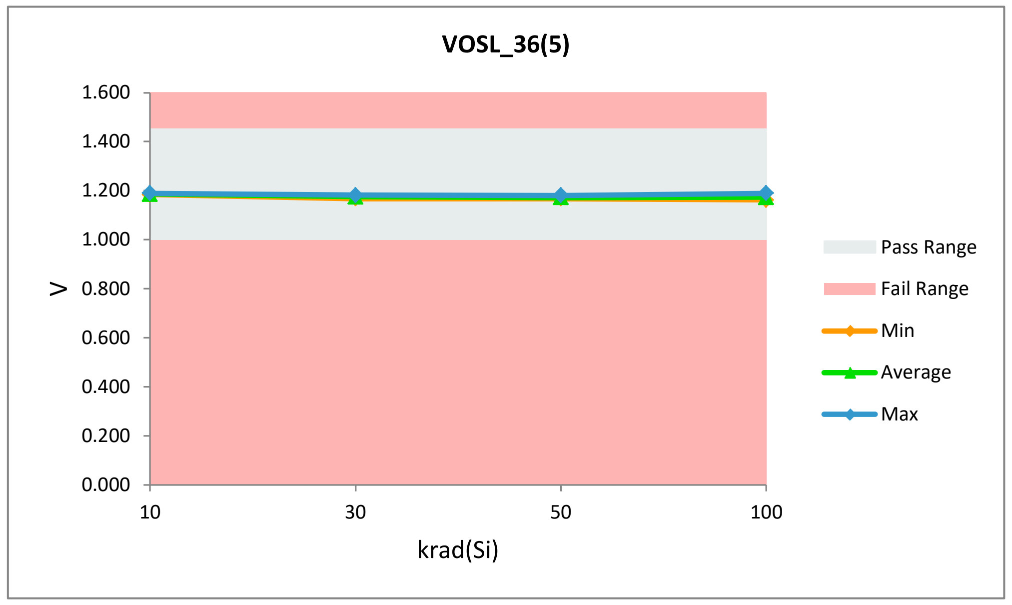
HDR UnBiased TID Report
SN55LVCP22A-SP

	VOSL_36(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.168	1.184	-0.016
10	7	1.183	1.189	-0.006
10	8	1.189	1.186	0.003
10	9	1.194	1.187	0.007
10	10	1.171	1.186	-0.015
30	6	1.179	1.180	-0.001
30	7	1.167	1.168	-0.001
30	8	1.173	1.171	0.002
30	9	1.183	1.174	0.009
30	10	1.179	1.182	-0.003
50	16	1.170	1.181	-0.011
50	17	1.167	1.172	-0.005
50	18	1.169	1.169	0.000
50	19	1.164	1.168	-0.004
50	20	1.180	1.170	0.010
100	B043	1.171	1.184	-0.013
100	B044	1.175	1.173	0.002
100	B045	1.182	1.167	0.015
100	B046	1.169	1.172	-0.003
100	B047	1.163	1.176	-0.013
100	B048	1.164	1.182	-0.018
100	B049	1.171	1.162	0.009
100	B050	1.171	1.169	0.002
100	B051	1.174	1.164	0.010
100	B052	1.175	1.167	0.008
100	B053	1.167	1.172	-0.005
100	B054	1.164	1.171	-0.007
100	B055	1.167	1.174	-0.007
100	B056	1.180	1.175	0.005
100	B057	1.189	1.167	0.022
100	B058	1.166	1.165	0.001
100	B059	1.170	1.169	0.001
100	B060	1.185	1.180	0.005
100	B061	1.173	1.189	-0.016
100	B062	1.167	1.168	-0.001
100	B063	1.169	1.171	-0.002
100	B064	1.171	1.185	-0.014
	Max	1.194	1.189	0.022
	Average	1.173	1.175	-0.001
	Min	1.163	1.162	-0.018
	Std Dev	0.008	0.008	0.009

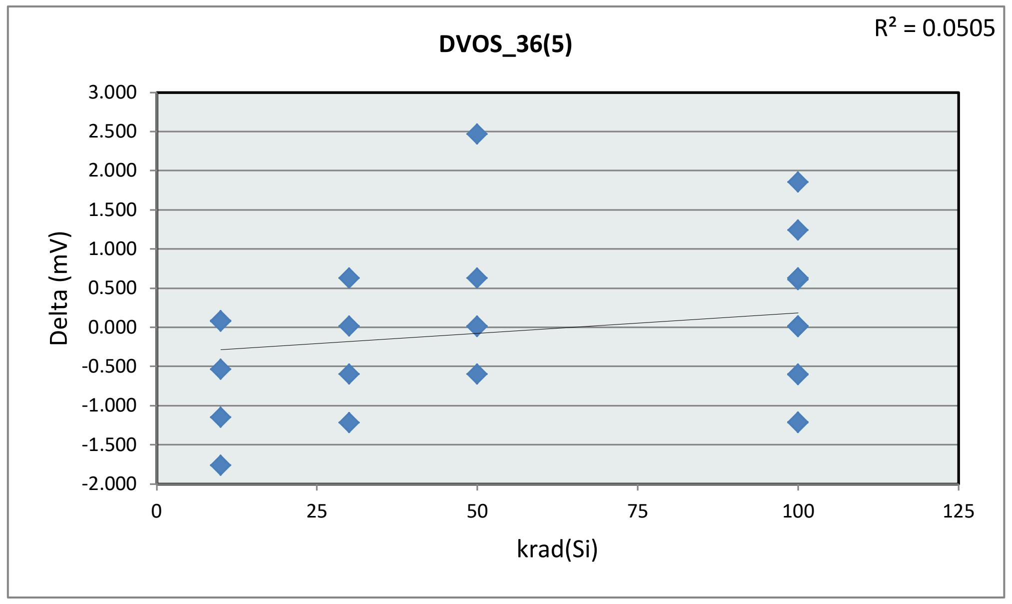


	VOSL_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.184	1.168	1.168	1.162
Average	1.186	1.175	1.172	1.173
Max	1.189	1.182	1.181	1.189
UL	1.450	1.450	1.450	1.450

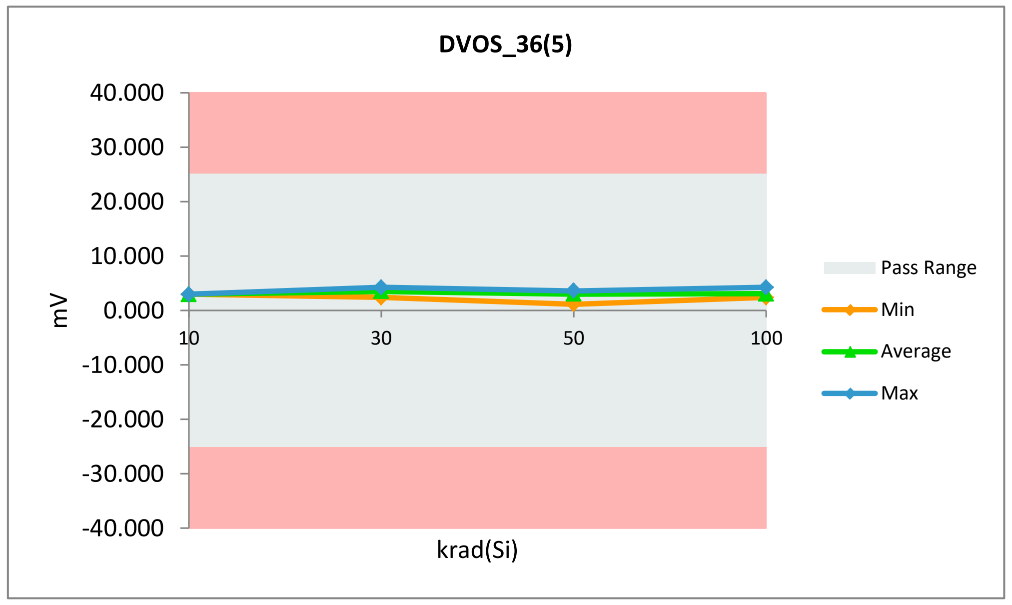


HDR UnBiased TID Report
SN55LVCP22A-SP

		DVOS_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.823	2.972	-1.149
10	7	3.050	2.969	0.081
10	8	1.209	2.970	-1.761
10	9	3.050	2.972	0.078
10	10	2.437	2.973	-0.536
30	6	3.026	2.401	0.625
30	7	3.641	3.630	0.011
30	8	4.253	3.628	0.625
30	9	3.026	4.242	-1.216
30	10	3.026	3.628	-0.602
50	16	3.641	1.175	2.466
50	17	3.641	3.629	0.012
50	18	3.027	3.629	-0.602
50	19	3.640	3.016	0.624
50	20	3.640	3.630	0.010
100	B043	2.413	3.015	-0.602
100	B044	3.026	3.015	0.011
100	B045	3.639	3.629	0.010
100	B046	3.027	2.402	0.625
100	B047	4.254	3.016	1.238
100	B048	3.027	3.014	0.013
100	B049	2.414	3.016	-0.602
100	B050	3.641	3.016	0.625
100	B051	4.254	4.242	0.012
100	B052	3.640	3.016	0.624
100	B053	3.026	3.016	0.010
100	B054	3.027	3.016	0.011
100	B055	3.640	3.629	0.011
100	B056	2.413	3.629	-1.216
100	B057	2.412	2.401	0.011
100	B058	3.026	3.017	0.009
100	B059	3.640	3.015	0.625
100	B060	4.254	2.402	1.852
100	B061	2.413	3.628	-1.215
100	B062	3.026	2.419	0.607
100	B063	3.640	3.015	0.625
100	B064	3.026	3.628	-0.602
	Max	4.254	4.242	2.466
	Average	3.162	3.126	0.036
	Min	1.209	1.175	-1.761
	Std Dev	0.676	0.576	0.841

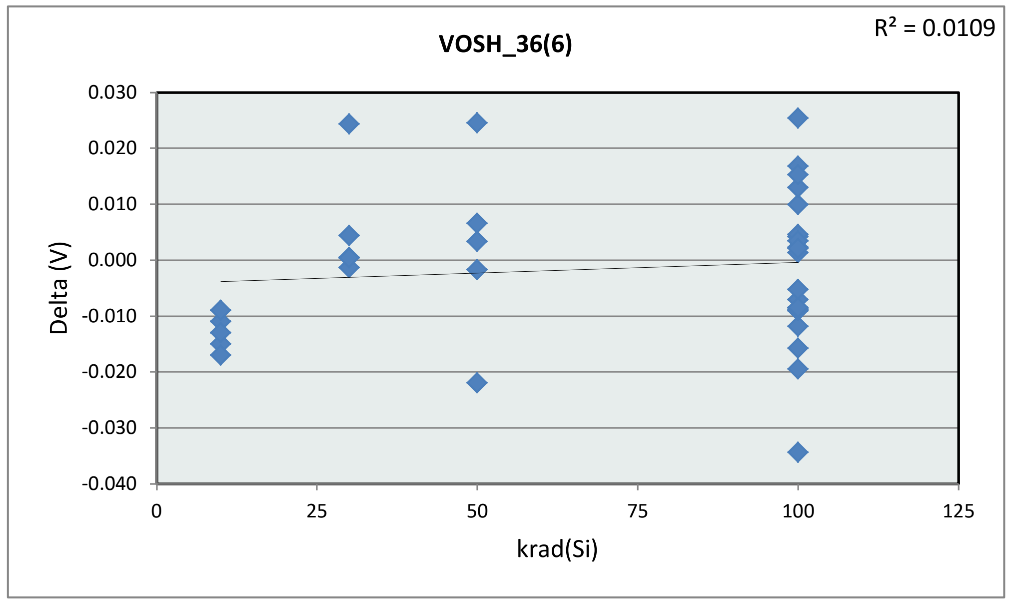


	DVOS_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.969	2.401	1.175	2.401
Average	2.971	3.506	3.016	3.100
Max	2.973	4.242	3.630	4.242
UL	25.000	25.000	25.000	25.000

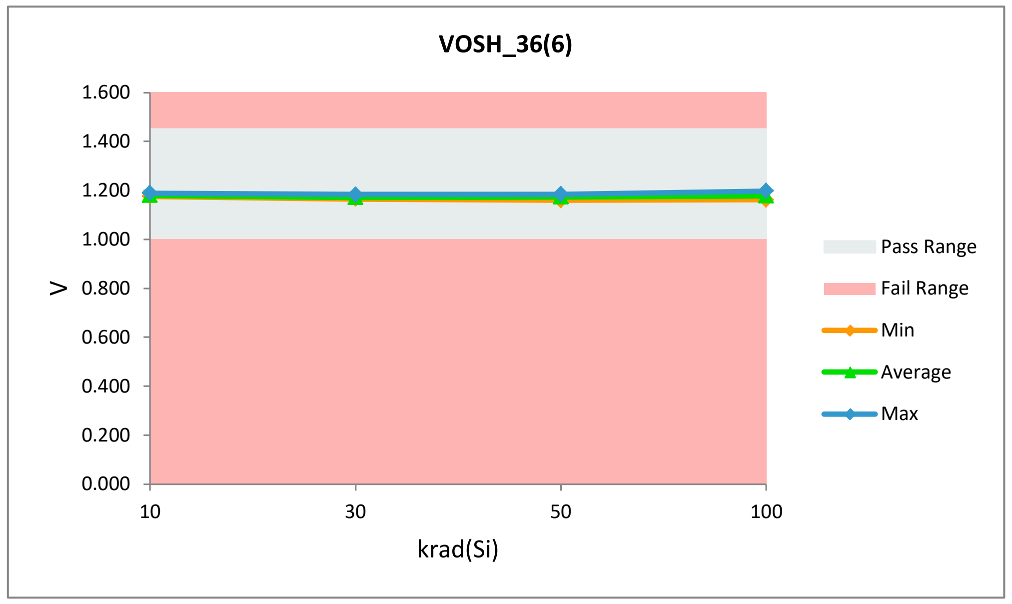


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSH_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.161	1.176	-0.015
10	7	1.169	1.180	-0.011
10	8	1.167	1.176	-0.009
10	9	1.176	1.189	-0.013
10	10	1.162	1.179	-0.017
30	6	1.182	1.183	-0.001
30	7	1.172	1.172	0.000
30	8	1.169	1.165	0.004
30	9	1.169	1.169	0.000
30	10	1.193	1.169	0.024
50	16	1.179	1.172	0.007
50	17	1.183	1.159	0.024
50	18	1.174	1.176	-0.002
50	19	1.162	1.184	-0.022
50	20	1.177	1.174	0.003
100	B043	1.171	1.180	-0.009
100	B044	1.182	1.180	0.002
100	B045	1.186	1.176	0.010
100	B046	1.196	1.171	0.025
100	B047	1.197	1.184	0.013
100	B048	1.178	1.185	-0.007
100	B049	1.171	1.167	0.004
100	B050	1.187	1.196	-0.009
100	B051	1.163	1.197	-0.034
100	B052	1.168	1.180	-0.012
100	B053	1.166	1.171	-0.005
100	B054	1.168	1.187	-0.019
100	B055	1.180	1.163	0.017
100	B056	1.172	1.169	0.003
100	B057	1.182	1.167	0.015
100	B058	1.159	1.168	-0.009
100	B059	1.187	1.182	0.005
100	B060	1.174	1.173	0.001
100	B061	1.176	1.184	-0.008
100	B062	1.164	1.161	0.003
100	B063	1.171	1.187	-0.016
100	B064	1.176	1.174	0.002
	Max	1.197	1.197	0.025
	Average	1.175	1.176	-0.001
	Min	1.159	1.159	-0.034
	Std Dev	0.010	0.009	0.013

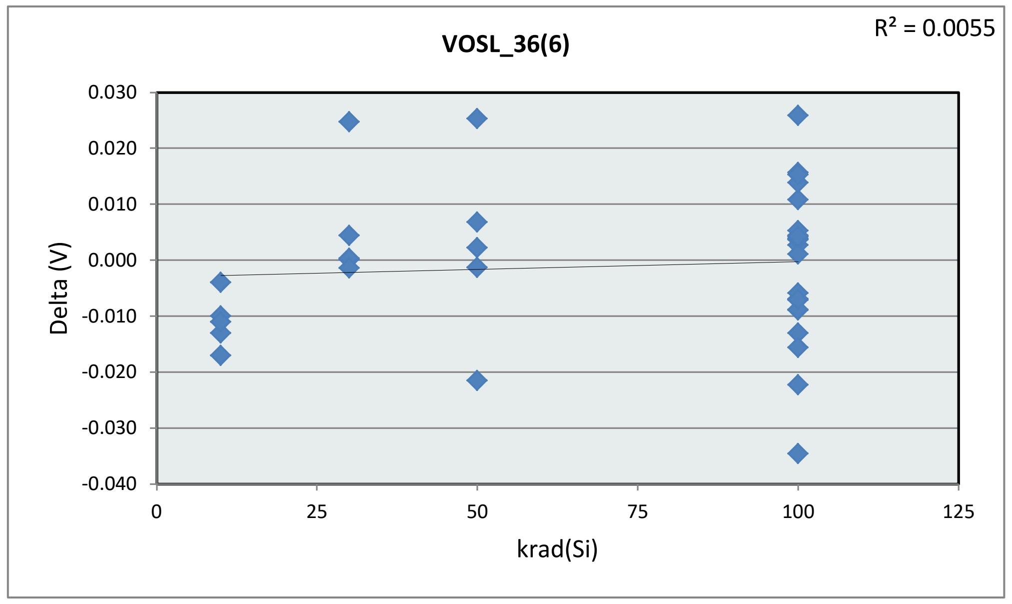


	VOSH_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.176	1.165	1.159	1.161
Average	1.180	1.172	1.173	1.177
Max	1.189	1.183	1.184	1.197
UL	1.450	1.450	1.450	1.450

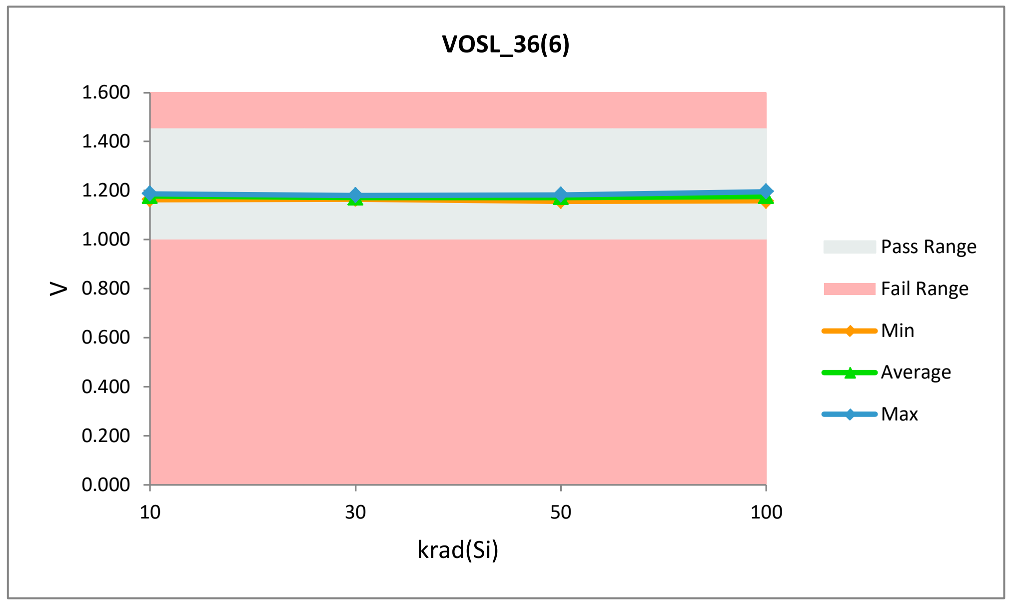


HDR UnBiased TID Report
SN55LVCP22A-SP

		VOSL_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	DR Unbiased LVCF	5 Post Test (Unbia	Delta
10	6	1.159	1.163	-0.004
10	7	1.167	1.180	-0.013
10	8	1.166	1.176	-0.010
10	9	1.176	1.187	-0.011
10	10	1.161	1.178	-0.017
30	6	1.181	1.181	0.000
30	7	1.171	1.171	0.000
30	8	1.169	1.165	0.004
30	9	1.168	1.169	-0.001
30	10	1.193	1.168	0.025
50	16	1.177	1.170	0.007
50	17	1.182	1.157	0.025
50	18	1.174	1.175	-0.001
50	19	1.161	1.183	-0.022
50	20	1.176	1.174	0.002
100	B043	1.170	1.179	-0.009
100	B044	1.182	1.179	0.003
100	B045	1.185	1.174	0.011
100	B046	1.196	1.170	0.026
100	B047	1.196	1.182	0.014
100	B048	1.178	1.185	-0.007
100	B049	1.171	1.167	0.004
100	B050	1.188	1.195	-0.007
100	B051	1.161	1.196	-0.035
100	B052	1.167	1.180	-0.013
100	B053	1.165	1.171	-0.006
100	B054	1.166	1.188	-0.022
100	B055	1.179	1.163	0.016
100	B056	1.172	1.168	0.004
100	B057	1.182	1.167	0.015
100	B058	1.157	1.166	-0.009
100	B059	1.185	1.181	0.004
100	B060	1.173	1.172	0.001
100	B061	1.175	1.182	-0.007
100	B062	1.163	1.158	0.005
100	B063	1.169	1.185	-0.016
100	B064	1.176	1.172	0.004
	Max	1.196	1.196	0.026
	Average	1.174	1.175	-0.001
	Min	1.157	1.157	-0.035
	Std Dev	0.010	0.009	0.013



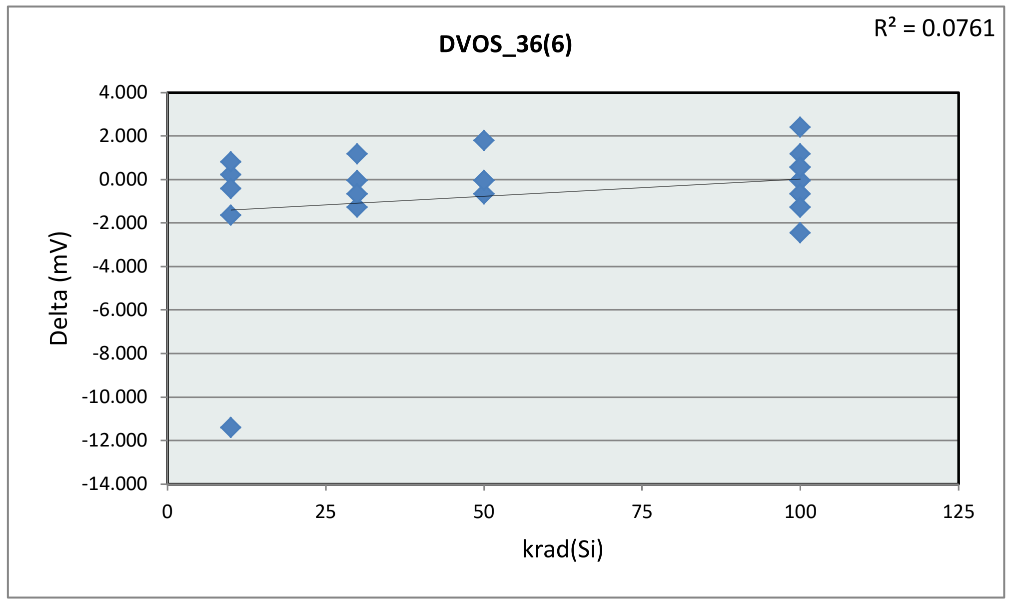
	VOSL_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.163	1.165	1.157	1.158
Average	1.177	1.171	1.172	1.176
Max	1.187	1.181	1.183	1.196
UL	1.450	1.450	1.450	1.450



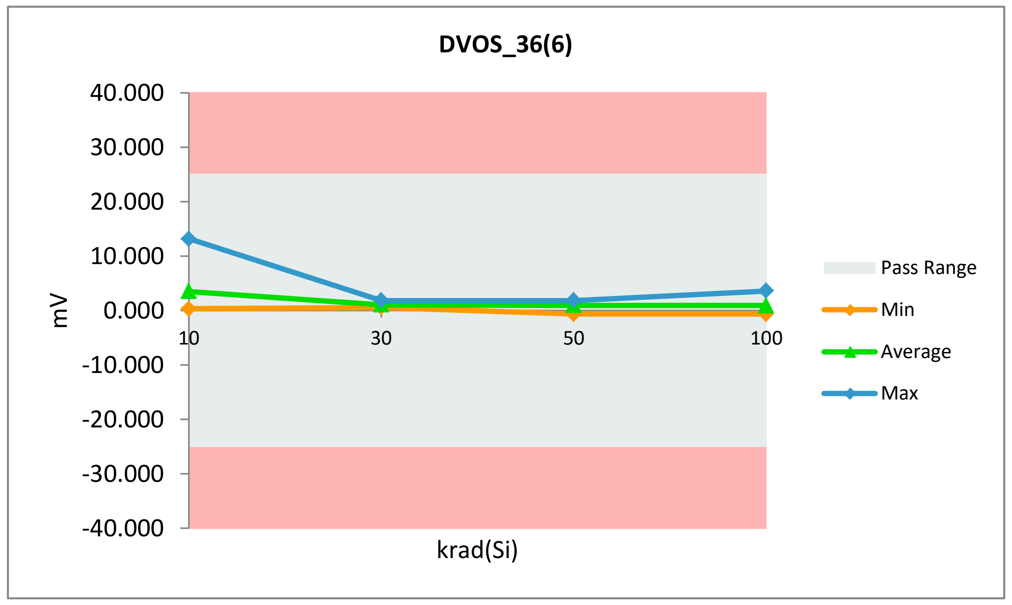
HDR UnBiased TID Report
SN55LVCP22A-SP

	DVOS_36(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	DR Unbiased LVCP	5 Post Test (Unbia	Delta
10	6	1.751	13.166	-11.415
10	7	1.136	0.931	0.205
10	8	1.136	0.324	0.812
10	9	-0.090	1.554	-1.644
10	10	1.136	1.552	-0.416
30	6	0.552	1.839	-1.287
30	7	1.168	1.225	-0.057
30	8	-0.062	0.611	-0.673
30	9	1.780	0.611	1.169
30	10	0.551	1.225	-0.674
50	16	1.781	1.839	-0.058
50	17	1.166	1.839	-0.673
50	18	0.552	1.225	-0.673
50	19	0.552	0.611	-0.059
50	20	1.165	-0.616	1.781
100	B043	1.166	1.225	-0.059
100	B044	0.553	0.611	-0.059
100	B045	1.164	1.839	-0.675
100	B046	0.553	1.225	-0.672
100	B047	1.164	1.225	-0.061
100	B048	-0.062	0.611	-0.673
100	B049	0.554	-0.002	0.557
100	B050	-0.676	0.611	-1.287
100	B051	1.167	1.225	-0.058
100	B052	1.167	-0.003	1.169
100	B053	0.551	-0.002	0.553
100	B054	1.780	-0.616	2.396
100	B055	1.166	0.611	0.554
100	B056	0.552	1.839	-1.287
100	B057	-0.063	-0.002	-0.061
100	B058	1.780	1.839	-0.059
100	B059	1.164	0.611	0.553
100	B060	1.166	0.611	0.555
100	B061	0.552	1.225	-0.673
100	B062	1.165	3.622	-2.457
100	B063	1.780	1.225	0.555
100	B064	-0.063	1.225	-1.288
	Max	1.781	13.166	2.396
	Average	0.880	1.316	-0.436
	Min	-0.676	-0.616	-11.415
	Std Dev	0.623	2.158	2.086



	DVOS_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.324	0.611	-0.616	-0.616
Average	3.505	1.102	0.980	0.943
Max	13.166	1.839	1.839	3.622
UL	25.000	25.000	25.000	25.000

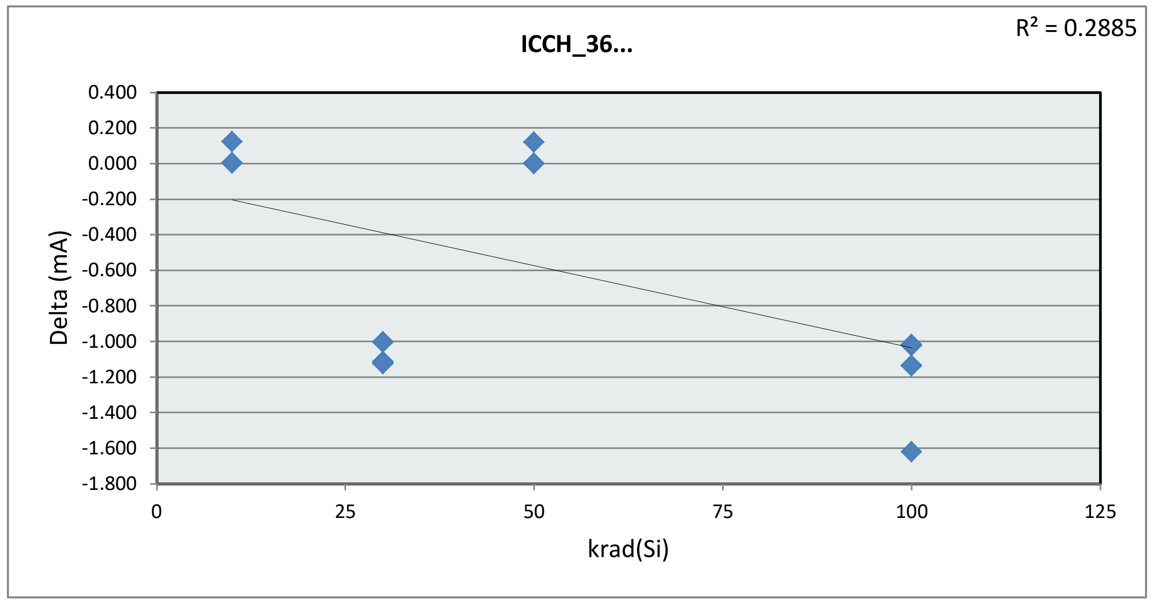


Delta Threshold	10.00%

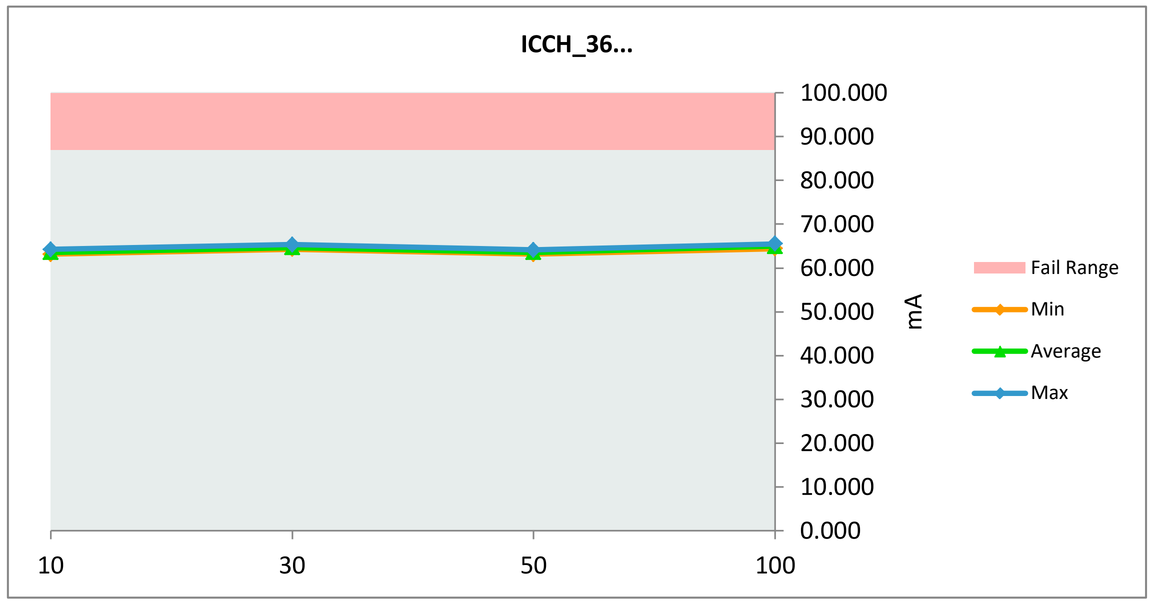
LDR Biased TID Report
SN55LVCP22A-SP

LDR Biased TID Report
SN55LVCP22A-SP

		ICCH_36...		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	87	87	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	63.397	63.395	0.002
10	5	64.237	64.236	0.002
10	7	63.517	63.515	0.002
10	11	63.877	63.876	0.002
10	15	63.397	63.395	0.002
10	20	63.397	63.275	0.122
10	21	63.157	63.155	0.001
10	24	63.637	63.636	0.001
30	1	63.397	64.520	-1.123
30	5	64.237	65.352	-1.115
30	7	63.517	64.520	-1.003
30	11	63.877	64.995	-1.118
30	15	63.397	64.520	-1.123
30	20	63.397	64.401	-1.004
30	21	63.157	64.282	-1.125
30	24	63.637	64.758	-1.121
50	1	63.397	63.397	0.000
50	5	64.237	64.117	0.120
50	7	63.517	63.517	0.000
50	11	63.877	63.877	0.000
50	15	63.397	63.397	0.000
50	20	63.397	63.397	0.000
50	21	63.157	63.157	0.000
50	24	63.637	63.637	0.000
100	3	64.117	65.254	-1.137
100	8	63.397	64.422	-1.025
100	12	64.357	65.492	-1.135
100	13	64.117	65.135	-1.018
100	16	63.637	64.660	-1.023
100	17	63.397	64.422	-1.025
100	18	63.397	65.017	-1.620
100	19	64.117	65.254	-1.137
	Max	64.357	65.492	0.122
	Average	63.637	64.187	-0.550
	Min	63.157	63.155	-1.620
	Std Dev	0.354	0.728	0.584

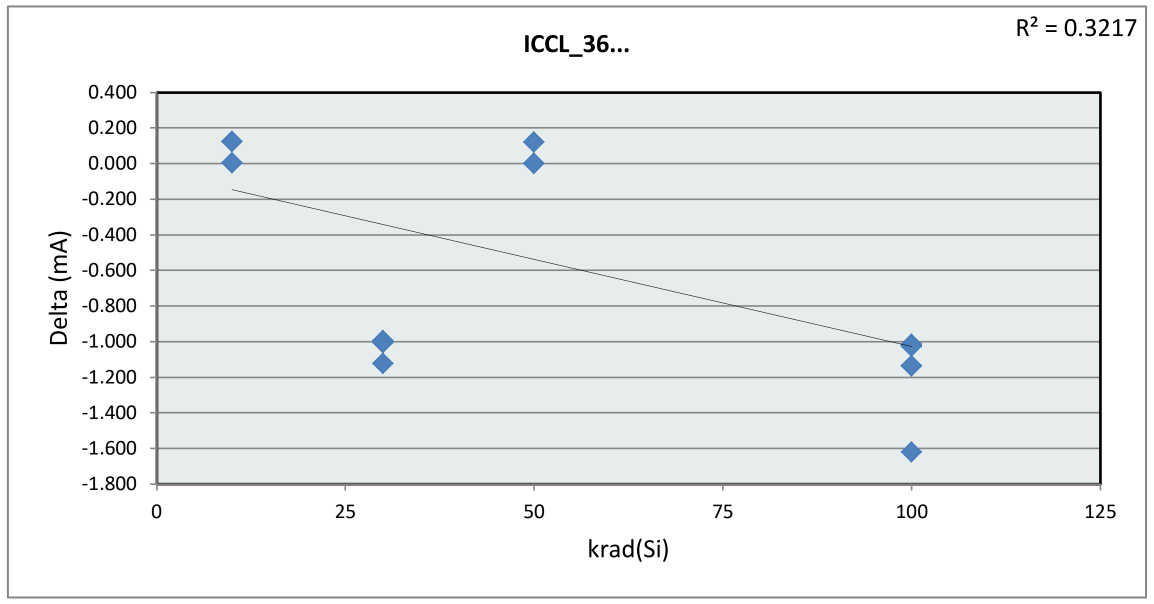


	ICCH_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	63.155	64.282	63.157	64.422
Average	63.560	64.669	63.562	64.957
Max	64.236	65.352	64.117	65.492
UL	87.000	87.000	87.000	87.000

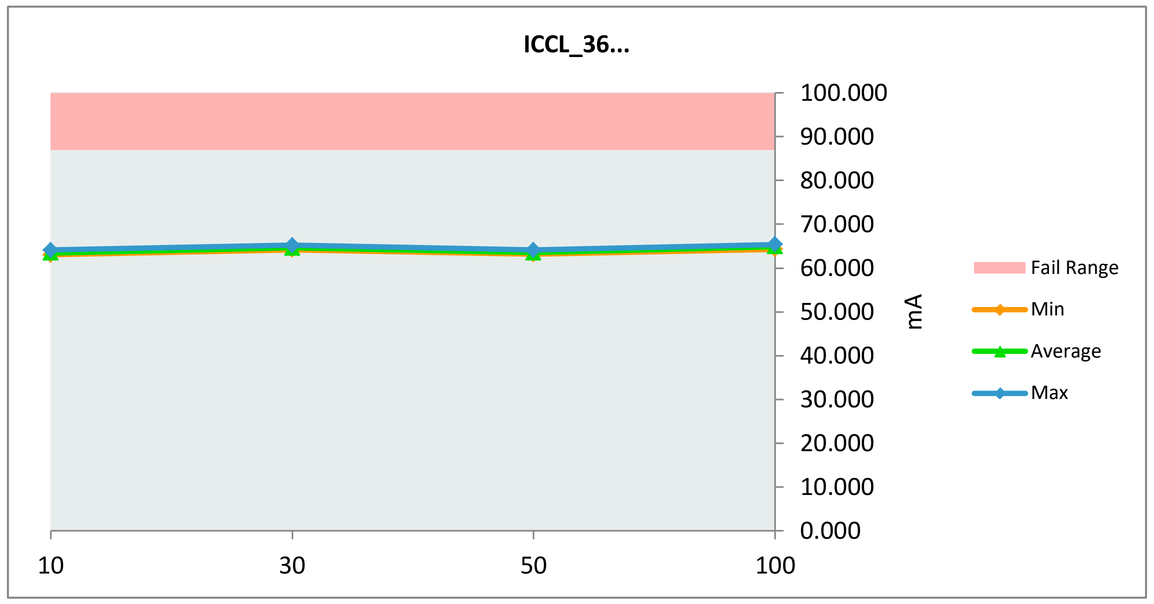


LDR Biased TID Report
SN55LVCP22A-SP

		ICCL_36...		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	87	87	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	63.397	63.275	0.122
10	5	64.237	64.116	0.122
10	7	63.397	63.395	0.002
10	11	63.877	63.756	0.122
10	15	63.397	63.395	0.002
10	20	63.277	63.275	0.002
10	21	63.157	63.035	0.122
10	24	63.637	63.515	0.122
30	1	63.397	64.401	-1.004
30	5	64.237	65.233	-0.996
30	7	63.397	64.520	-1.123
30	11	63.877	64.876	-0.999
30	15	63.397	64.520	-1.123
30	20	63.277	64.282	-1.005
30	21	63.157	64.163	-1.006
30	24	63.637	64.639	-1.002
50	1	63.397	63.397	0.000
50	5	64.237	64.117	0.120
50	7	63.397	63.397	0.000
50	11	63.877	63.877	0.000
50	15	63.397	63.397	0.000
50	20	63.277	63.277	0.000
50	21	63.157	63.157	0.000
50	24	63.637	63.517	0.120
100	3	64.117	65.135	-1.018
100	8	63.277	64.303	-1.026
100	12	64.357	65.373	-1.016
100	13	63.997	65.135	-1.138
100	16	63.637	64.660	-1.023
100	17	63.397	64.422	-1.025
100	18	63.397	65.017	-1.620
100	19	64.117	65.254	-1.137
	Max	64.357	65.373	0.122
	Average	63.607	64.120	-0.513
	Min	63.157	63.035	-1.620
	Std Dev	0.367	0.728	0.587



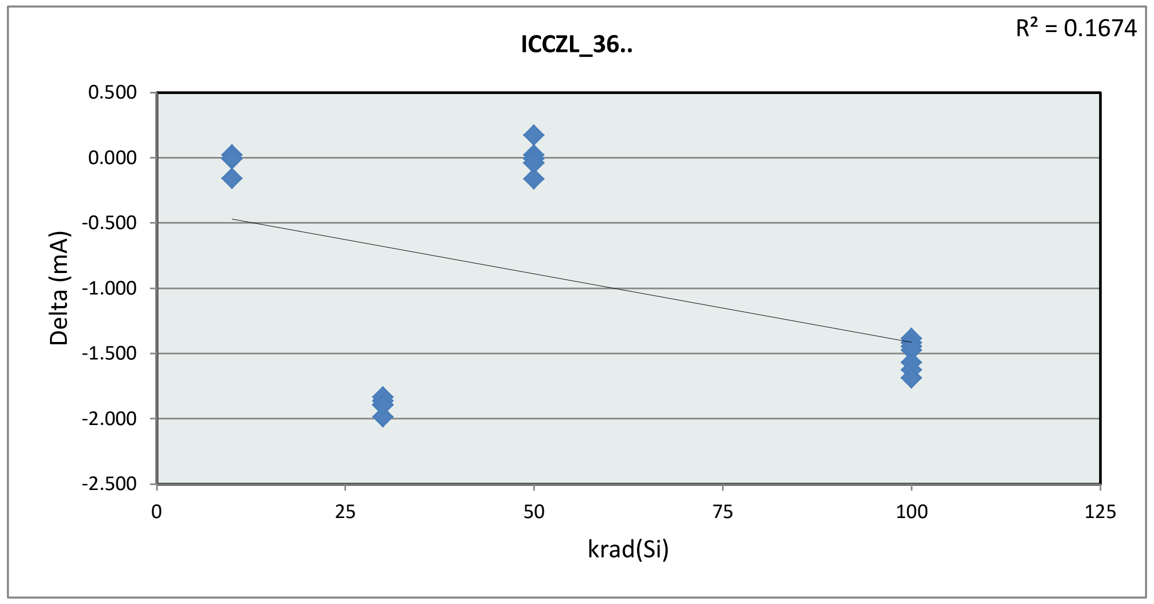
	ICCL_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	63.035	64.163	63.157	64.303
Average	63.470	64.579	63.517	64.912
Max	64.116	65.233	64.117	65.373
UL	87.000	87.000	87.000	87.000



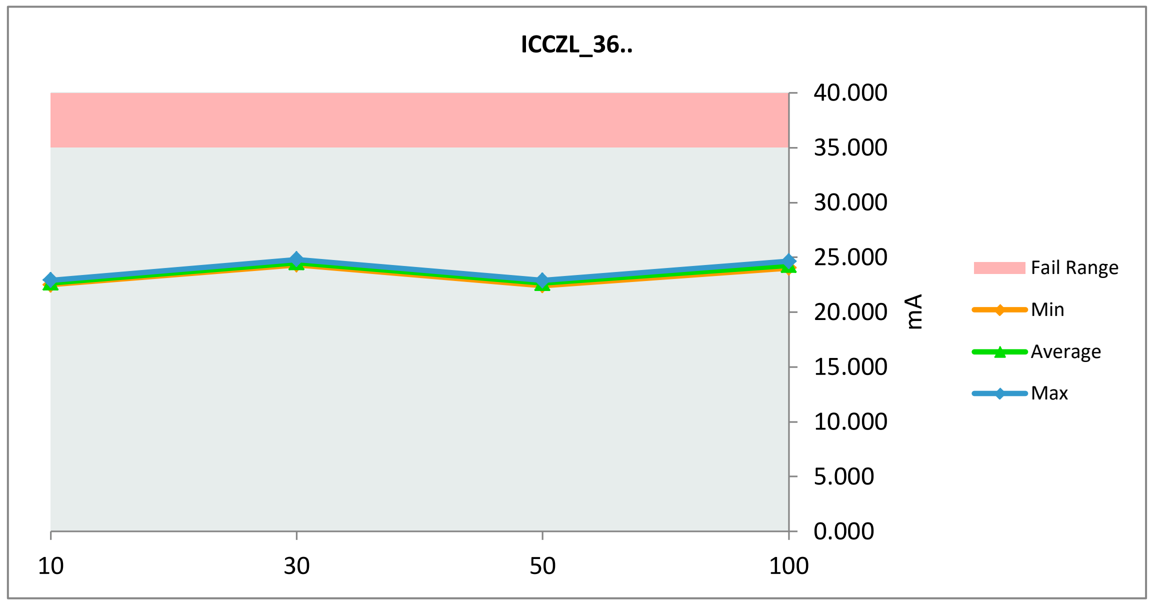
LDR Biased TID Report
SN55LVCP22A-SP

	ICCZL_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	22.609	22.618	-0.009
10	5	22.912	22.922	-0.009
10	7	22.609	22.618	-0.009
10	11	22.791	22.800	-0.010
10	15	22.639	22.618	0.021
10	20	22.518	22.527	-0.009
10	21	22.336	22.497	-0.161
10	24	22.730	22.740	-0.009
30	1	22.609	24.444	-1.835
30	5	22.912	24.806	-1.894
30	7	22.609	24.474	-1.865
30	11	22.791	24.686	-1.895
30	15	22.639	24.474	-1.835
30	20	22.518	24.354	-1.836
30	21	22.336	24.323	-1.987
30	24	22.730	24.625	-1.895
50	1	22.609	22.437	0.172
50	5	22.912	22.892	0.020
50	7	22.609	22.619	-0.010
50	11	22.791	22.831	-0.041
50	15	22.639	22.649	-0.010
50	20	22.518	22.558	-0.041
50	21	22.336	22.498	-0.162
50	24	22.730	22.771	-0.041
100	3	22.882	24.358	-1.476
100	8	22.669	24.056	-1.387
100	12	22.942	24.630	-1.688
100	13	22.609	24.177	-1.568
100	16	22.639	24.056	-1.417
100	17	22.578	24.026	-1.448
100	18	22.609	24.237	-1.628
100	19	22.912	24.599	-1.687
	Max	22.942	24.806	0.172
	Average	22.665	23.529	-0.864
	Min	22.336	22.437	-1.987
	Std Dev	0.166	0.902	0.871



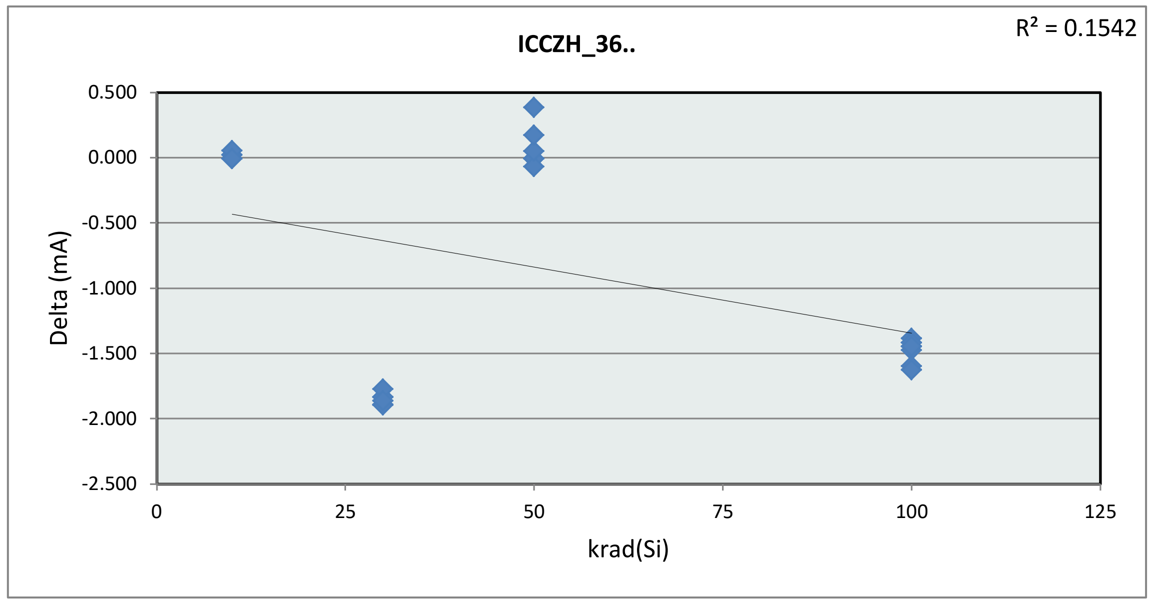
	ICCZL_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	22.497	24.323	22.437	24.026
Average	22.667	24.523	22.657	24.267
Max	22.922	24.806	22.892	24.630
UL	35.000	35.000	35.000	35.000



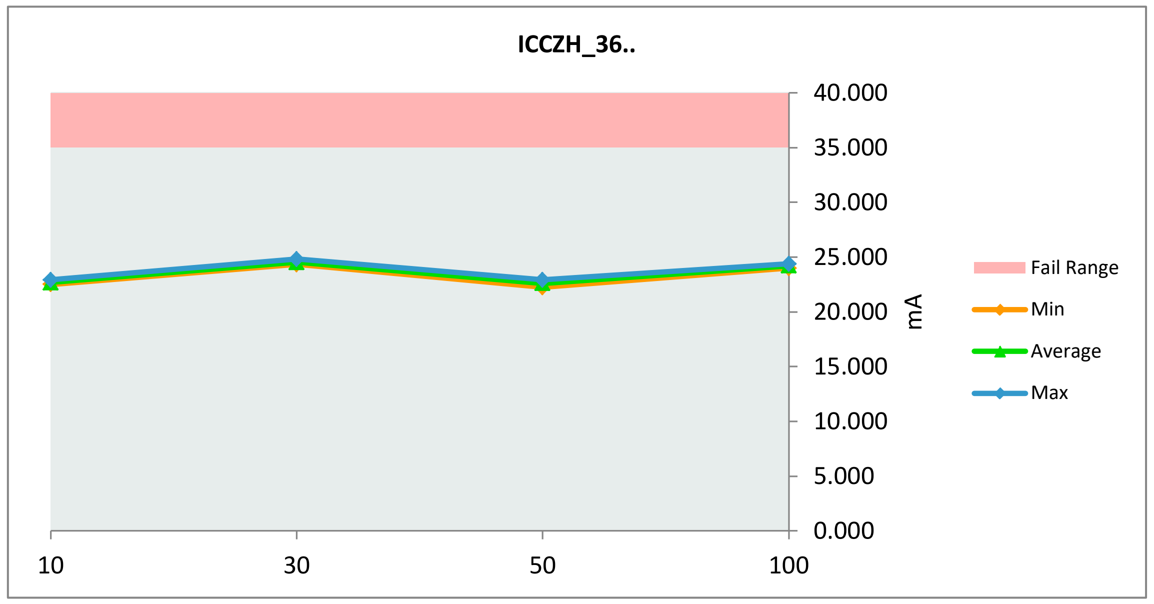
LDR Biased TID Report
SN55LVCP22A-SP

	ICCZH_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	22.609	22.588	0.021
10	5	22.912	22.922	-0.009
10	7	22.609	22.618	-0.009
10	11	22.791	22.800	-0.010
10	15	22.639	22.618	0.021
10	20	22.518	22.527	-0.009
10	21	22.548	22.497	0.051
10	24	22.730	22.740	-0.009
30	1	22.609	24.444	-1.835
30	5	22.912	24.806	-1.894
30	7	22.609	24.444	-1.835
30	11	22.791	24.686	-1.895
30	15	22.639	24.474	-1.835
30	20	22.518	24.354	-1.836
30	21	22.548	24.323	-1.775
30	24	22.730	24.595	-1.865
50	1	22.609	22.224	0.384
50	5	22.912	22.923	-0.010
50	7	22.609	22.619	-0.010
50	11	22.791	22.801	-0.010
50	15	22.639	22.649	-0.010
50	20	22.518	22.589	-0.071
50	21	22.548	22.498	0.050
50	24	22.730	22.558	0.172
100	3	22.882	24.358	-1.476
100	8	22.669	24.056	-1.387
100	12	22.942	24.388	-1.446
100	13	22.578	24.177	-1.599
100	16	22.639	24.056	-1.417
100	17	22.578	23.996	-1.418
100	18	22.609	24.237	-1.628
100	19	22.912	24.358	-1.446
	Max	22.942	24.806	0.384
	Average	22.684	23.498	-0.814
	Min	22.518	22.224	-1.895
	Std Dev	0.135	0.898	0.876

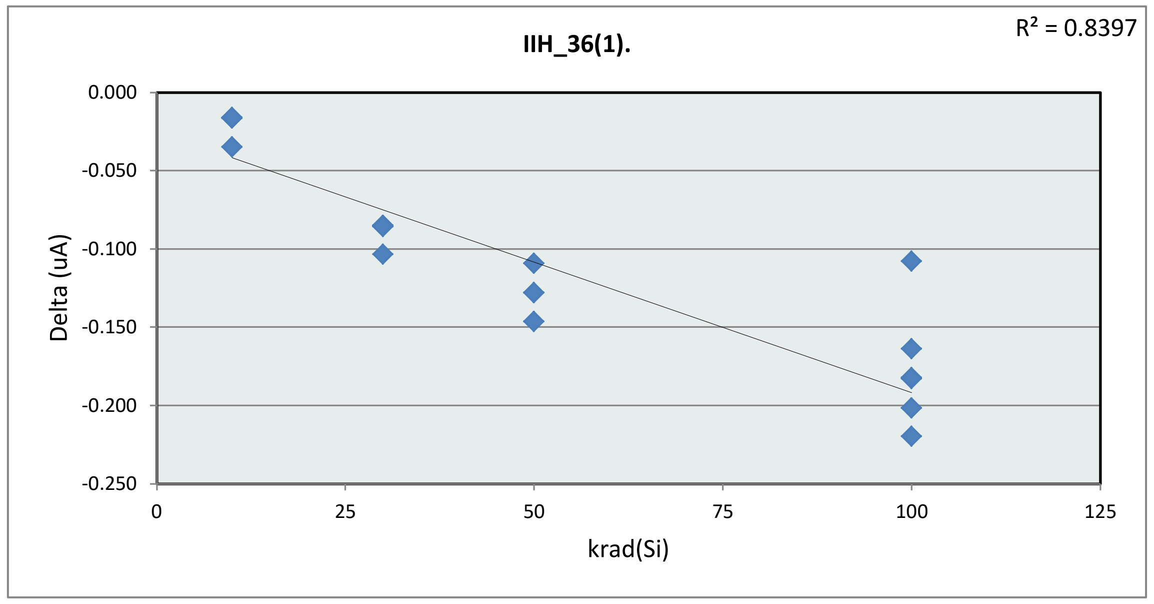


	ICCZH_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	22.497	24.323	22.224	23.996
Average	22.664	24.516	22.608	24.203
Max	22.922	24.806	22.923	24.388
UL	35.000	35.000	35.000	35.000

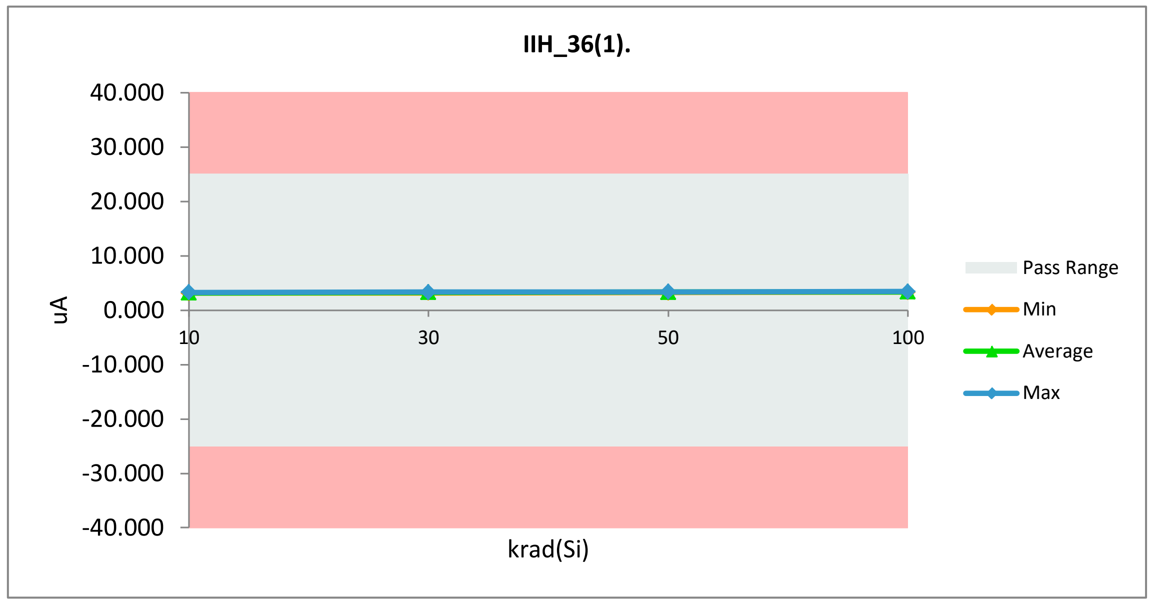


LDR Biased TID Report
SN55LVCP22A-SP

		IIH_36(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.125	3.141	-0.016
10	5	3.125	3.141	-0.016
10	7	3.199	3.234	-0.035
10	11	3.181	3.216	-0.035
10	15	3.274	3.290	-0.016
10	20	3.255	3.272	-0.016
10	21	3.199	3.216	-0.016
10	24	3.162	3.178	-0.016
30	1	3.125	3.210	-0.085
30	5	3.125	3.210	-0.085
30	7	3.199	3.303	-0.104
30	11	3.181	3.266	-0.085
30	15	3.274	3.359	-0.085
30	20	3.255	3.341	-0.086
30	21	3.199	3.285	-0.086
30	24	3.162	3.248	-0.086
50	1	3.125	3.253	-0.128
50	5	3.125	3.234	-0.109
50	7	3.199	3.346	-0.147
50	11	3.181	3.327	-0.147
50	15	3.274	3.402	-0.128
50	20	3.255	3.383	-0.128
50	21	3.199	3.309	-0.109
50	24	3.162	3.290	-0.128
100	3	3.106	3.326	-0.220
100	8	3.162	3.345	-0.183
100	12	3.162	3.326	-0.164
100	13	3.199	3.401	-0.202
100	16	3.237	3.419	-0.182
100	17	3.199	3.401	-0.202
100	18	3.255	3.363	-0.108
100	19	3.143	3.326	-0.183
	Max	3.274	3.419	-0.016
	Average	3.188	3.293	-0.104
	Min	3.106	3.141	-0.220
	Std Dev	0.051	0.076	0.062



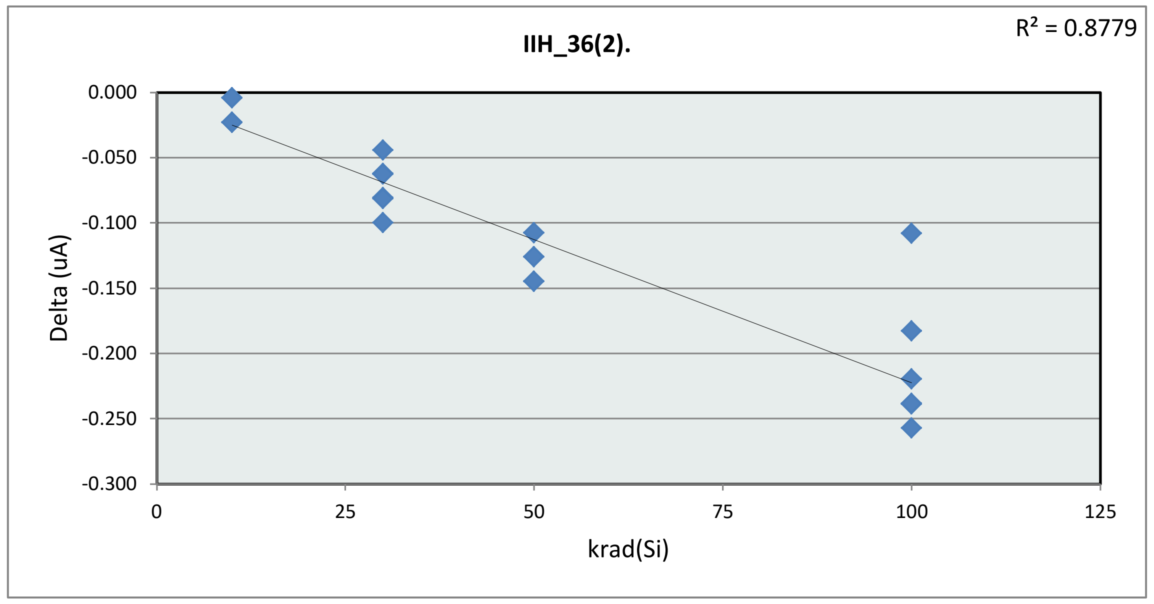
	IIH_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.141	3.210	3.234	3.326
Average	3.211	3.278	3.318	3.363
Max	3.290	3.359	3.402	3.419
UL	25.000	25.000	25.000	25.000



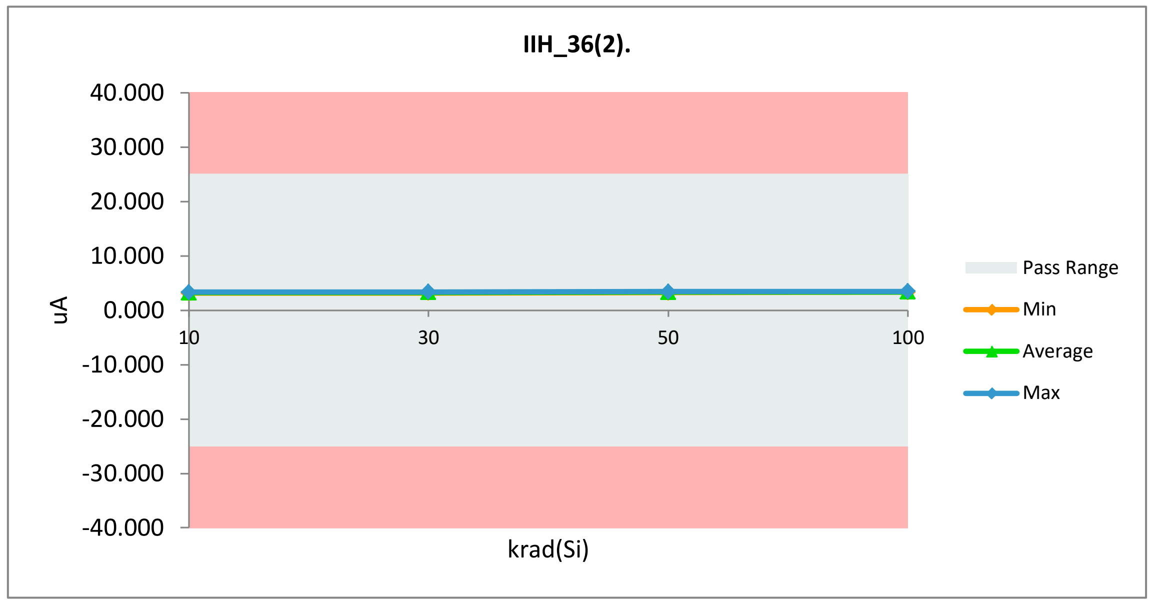
LDR Biased TID Report
SN55LVCP22A-SP

	IIH_36(2).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.126	3.149	-0.023
10	5	3.107	3.130	-0.023
10	7	3.256	3.279	-0.023
10	11	3.182	3.205	-0.023
10	15	3.238	3.260	-0.023
10	20	3.330	3.335	-0.004
10	21	3.238	3.242	-0.004
10	24	3.163	3.168	-0.004
30	1	3.126	3.226	-0.100
30	5	3.107	3.170	-0.063
30	7	3.256	3.337	-0.081
30	11	3.182	3.244	-0.062
30	15	3.238	3.319	-0.081
30	20	3.330	3.375	-0.045
30	21	3.238	3.300	-0.062
30	24	3.163	3.226	-0.063
50	1	3.126	3.271	-0.145
50	5	3.107	3.215	-0.108
50	7	3.256	3.401	-0.145
50	11	3.182	3.308	-0.126
50	15	3.238	3.382	-0.145
50	20	3.330	3.457	-0.126
50	21	3.238	3.345	-0.108
50	24	3.163	3.289	-0.126
100	3	3.126	3.365	-0.239
100	8	3.126	3.365	-0.239
100	12	3.163	3.346	-0.183
100	13	3.182	3.439	-0.257
100	16	3.200	3.420	-0.220
100	17	3.238	3.476	-0.238
100	18	3.312	3.420	-0.108
100	19	3.145	3.383	-0.238
	Max	3.330	3.476	-0.004
	Average	3.200	3.308	-0.107
	Min	3.107	3.130	-0.257
	Std Dev	0.069	0.093	0.080



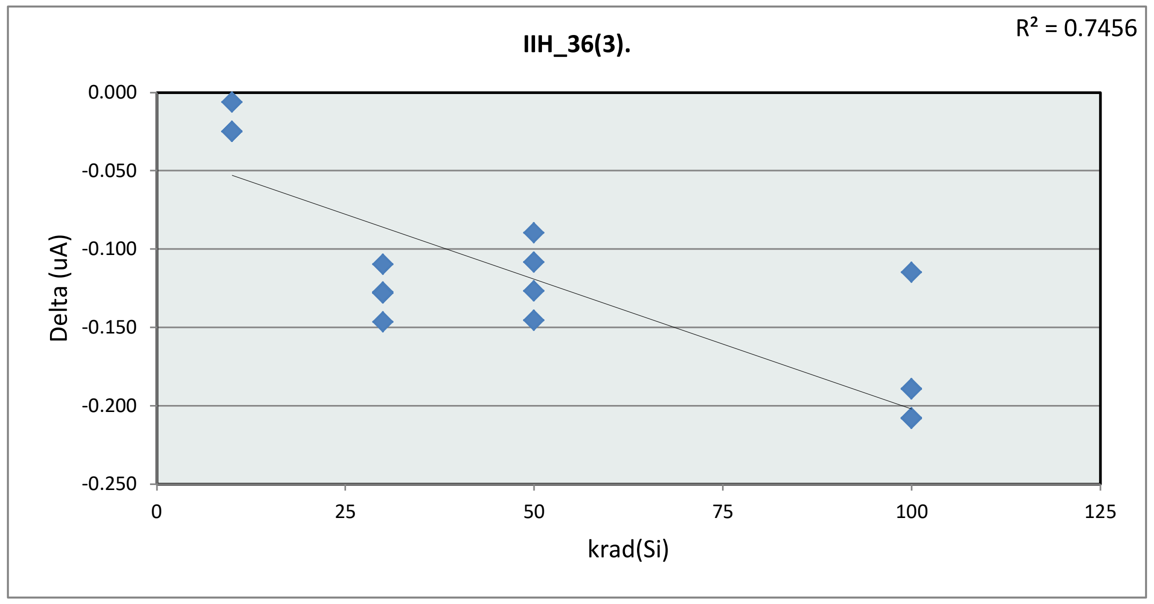
	IIH_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.130	3.170	3.215	3.346
Average	3.221	3.275	3.334	3.402
Max	3.335	3.375	3.457	3.476
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
SN55LVCP22A-SP

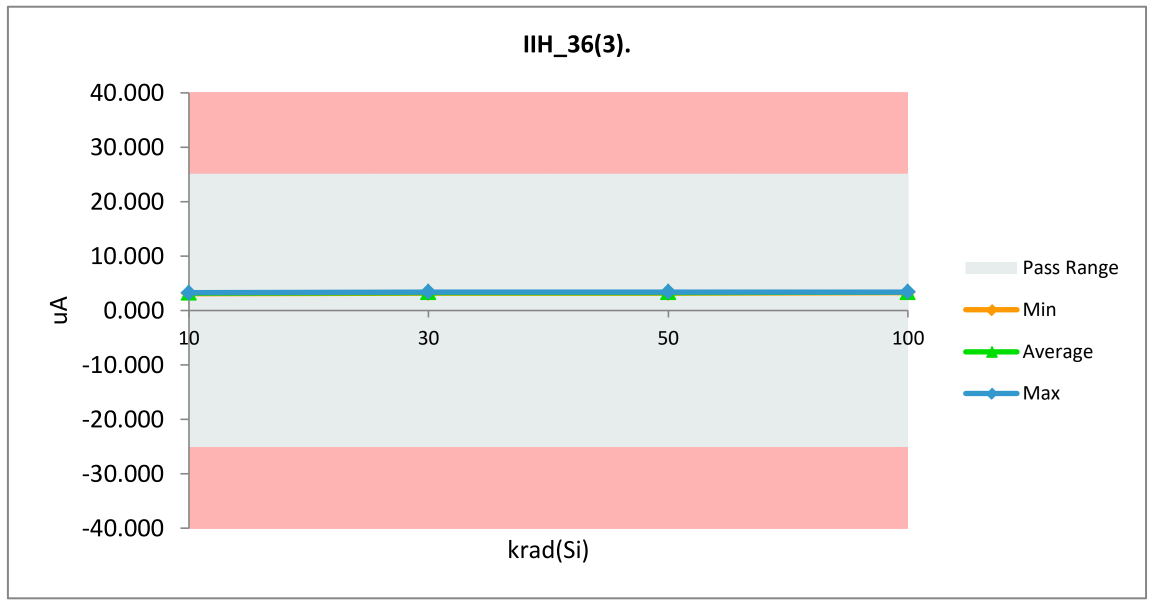
	IIH_36(3).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.144	3.169	-0.025
10	5	3.125	3.150	-0.025
10	7	3.200	3.225	-0.025
10	11	3.181	3.206	-0.025
10	15	3.274	3.299	-0.025
10	20	3.274	3.280	-0.006
10	21	3.218	3.225	-0.006
10	24	3.144	3.169	-0.025
30	1	3.144	3.272	-0.128
30	5	3.125	3.235	-0.110
30	7	3.200	3.328	-0.128
30	11	3.181	3.309	-0.128
30	15	3.274	3.421	-0.147
30	20	3.274	3.384	-0.110
30	21	3.218	3.346	-0.128
30	24	3.144	3.272	-0.128
50	1	3.144	3.271	-0.127
50	5	3.125	3.215	-0.090
50	7	3.200	3.345	-0.146
50	11	3.181	3.308	-0.127
50	15	3.274	3.420	-0.146
50	20	3.274	3.383	-0.108
50	21	3.218	3.327	-0.108
50	24	3.144	3.271	-0.127
100	3	3.125	3.333	-0.208
100	8	3.144	3.333	-0.189
100	12	3.162	3.352	-0.190
100	13	3.200	3.408	-0.208
100	16	3.237	3.445	-0.208
100	17	3.200	3.408	-0.208
100	18	3.274	3.389	-0.115
100	19	3.125	3.333	-0.208
	Max	3.274	3.445	-0.006
	Average	3.192	3.307	-0.115
	Min	3.125	3.150	-0.208
	Std Dev	0.054	0.080	0.065



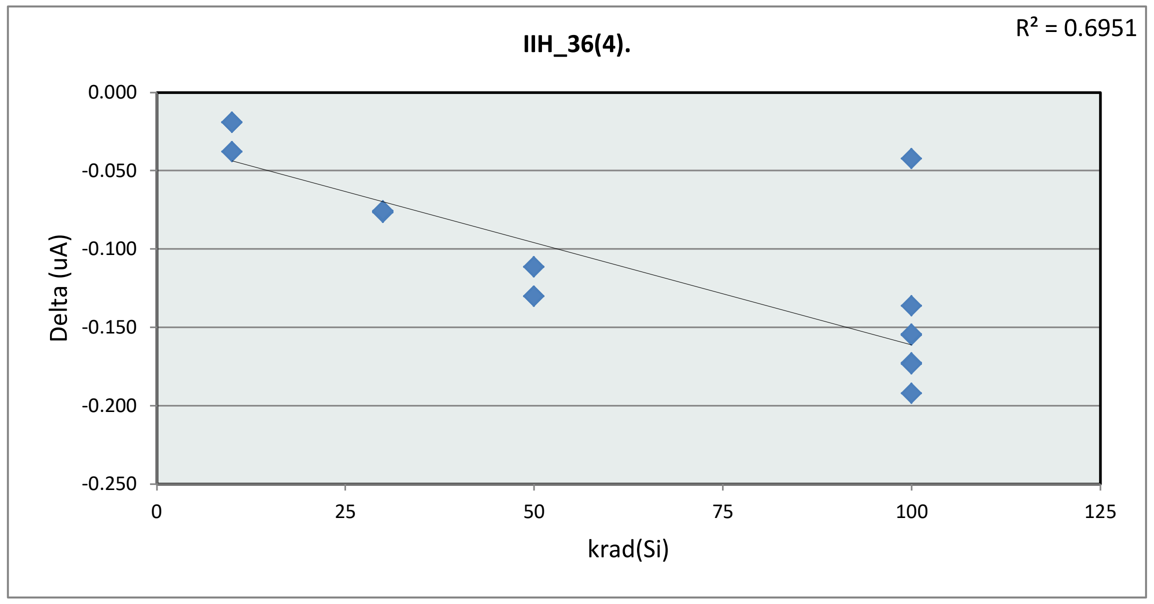
	IIH_36(3).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.150	3.235	3.215	3.333
Average	3.215	3.321	3.317	3.375
Max	3.299	3.421	3.420	3.445
UL	25.000	25.000	25.000	25.000

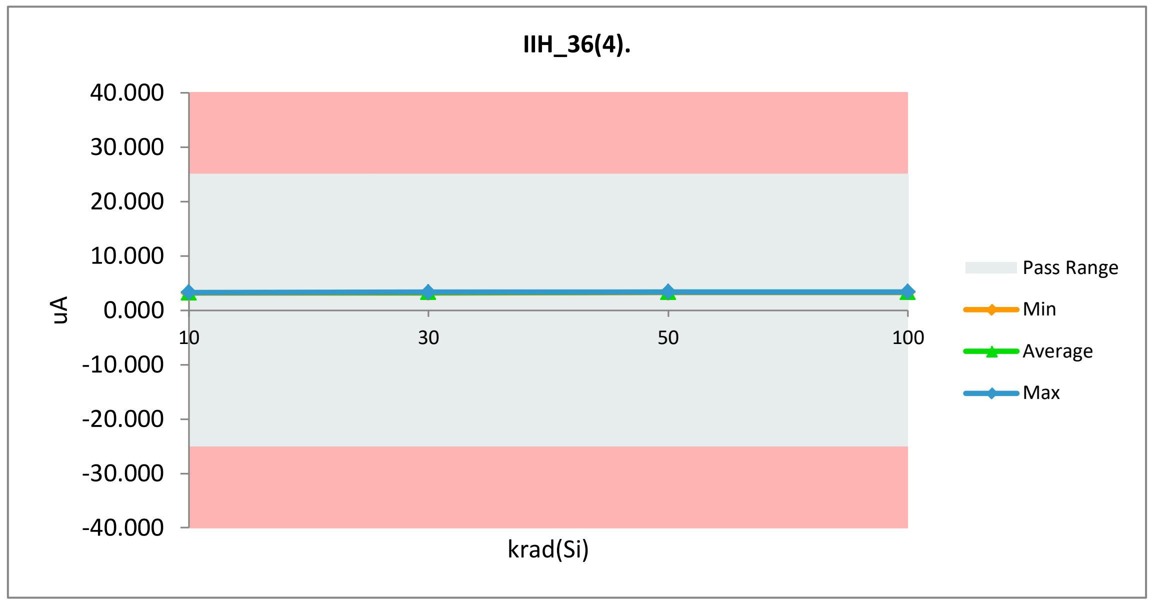


LDR Biased TID Report
SN55LVCP22A-SP

		IIH_36(4).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.129	3.149	-0.019
10	5	3.111	3.149	-0.038
10	7	3.204	3.223	-0.019
10	11	3.185	3.205	-0.019
10	15	3.278	3.298	-0.019
10	20	3.260	3.298	-0.038
10	21	3.204	3.223	-0.019
10	24	3.148	3.167	-0.019
30	1	3.129	3.206	-0.077
30	5	3.111	3.187	-0.076
30	7	3.204	3.280	-0.076
30	11	3.185	3.262	-0.077
30	15	3.278	3.355	-0.077
30	20	3.260	3.336	-0.076
30	21	3.204	3.280	-0.076
30	24	3.148	3.224	-0.076
50	1	3.129	3.260	-0.130
50	5	3.111	3.222	-0.112
50	7	3.204	3.316	-0.112
50	11	3.185	3.316	-0.130
50	15	3.278	3.409	-0.130
50	20	3.260	3.390	-0.130
50	21	3.204	3.316	-0.112
50	24	3.148	3.278	-0.130
100	3	3.111	3.303	-0.192
100	8	3.148	3.321	-0.173
100	12	3.167	3.303	-0.136
100	13	3.204	3.359	-0.155
100	16	3.241	3.396	-0.155
100	17	3.185	3.359	-0.174
100	18	3.278	3.321	-0.043
100	19	3.129	3.284	-0.155
	Max	3.278	3.409	-0.019
	Average	3.188	3.281	-0.093
	Min	3.111	3.149	-0.192
	Std Dev	0.056	0.070	0.053

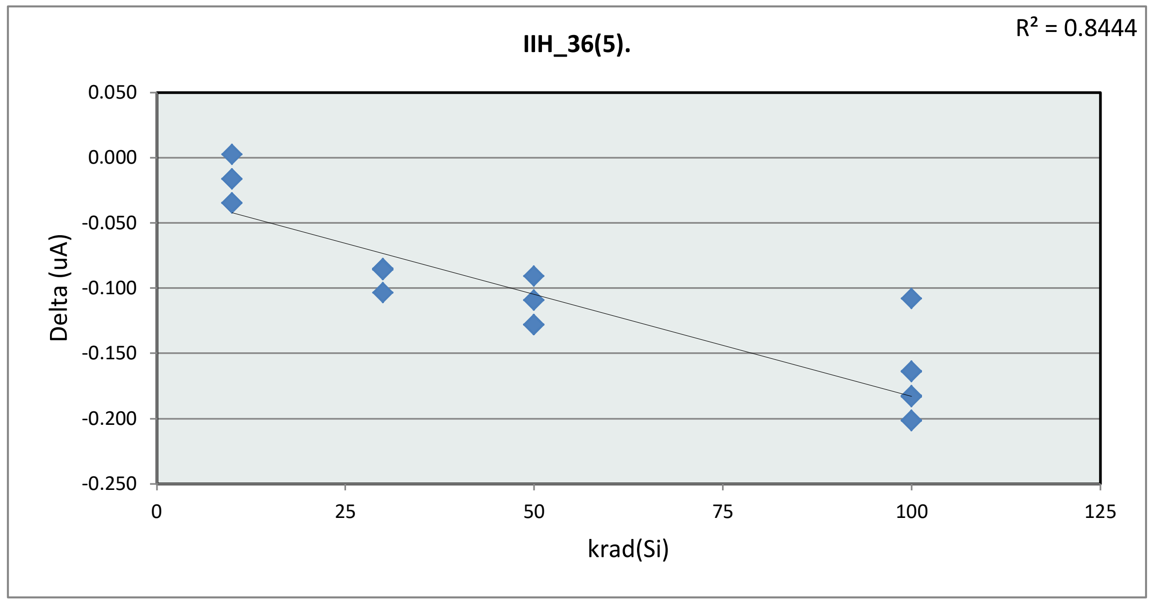


	IIH_36(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.149	3.187	3.222	3.284
Average	3.214	3.266	3.313	3.331
Max	3.298	3.355	3.409	3.396
UL	25.000	25.000	25.000	25.000

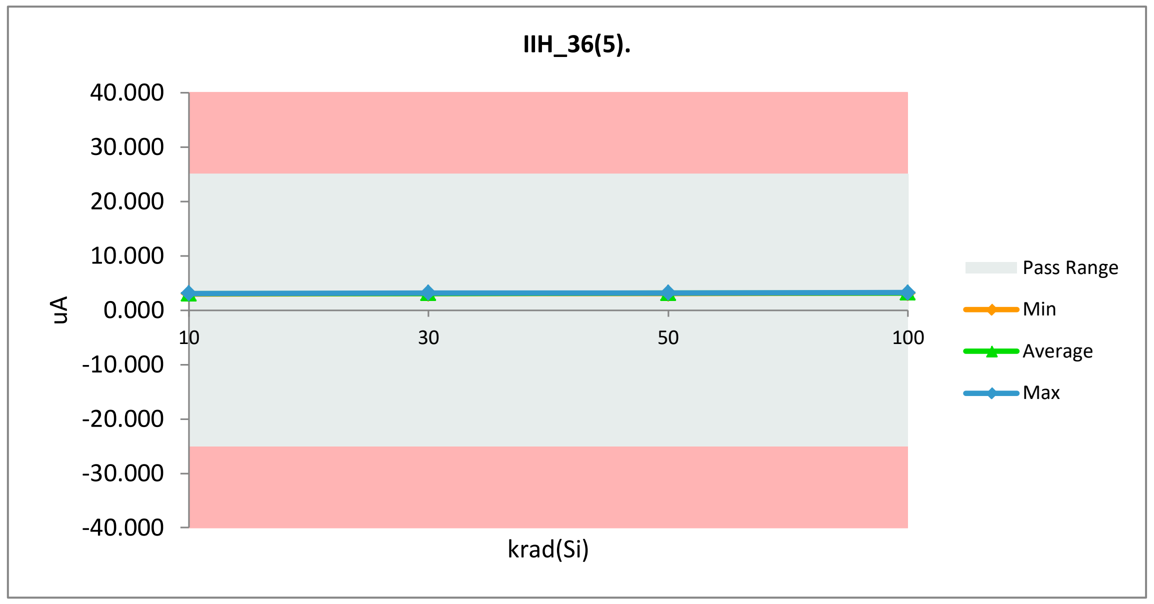


LDR Biased TID Report
SN55LVCP22A-SP

		IIH_36(5).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	2.957	2.974	-0.016
10	5	2.939	2.974	-0.035
10	7	3.032	3.048	-0.016
10	11	2.994	3.029	-0.035
10	15	3.088	3.085	0.002
10	20	3.069	3.104	-0.035
10	21	3.013	3.029	-0.016
10	24	2.957	2.992	-0.035
30	1	2.957	3.043	-0.086
30	5	2.939	3.024	-0.085
30	7	3.032	3.117	-0.085
30	11	2.994	3.080	-0.086
30	15	3.088	3.173	-0.085
30	20	3.069	3.155	-0.086
30	21	3.013	3.099	-0.086
30	24	2.957	3.061	-0.104
50	1	2.957	3.085	-0.128
50	5	2.939	3.048	-0.109
50	7	3.032	3.160	-0.128
50	11	2.994	3.122	-0.128
50	15	3.088	3.197	-0.109
50	20	3.069	3.197	-0.128
50	21	3.013	3.104	-0.091
50	24	2.957	3.085	-0.128
100	3	2.957	3.140	-0.183
100	8	2.976	3.159	-0.183
100	12	2.976	3.140	-0.164
100	13	2.994	3.196	-0.202
100	16	3.032	3.215	-0.183
100	17	3.013	3.215	-0.202
100	18	3.069	3.177	-0.108
100	19	2.957	3.121	-0.164
	Max	3.088	3.215	0.002
	Average	3.004	3.105	-0.101
	Min	2.939	2.974	-0.202
	Std Dev	0.049	0.070	0.058



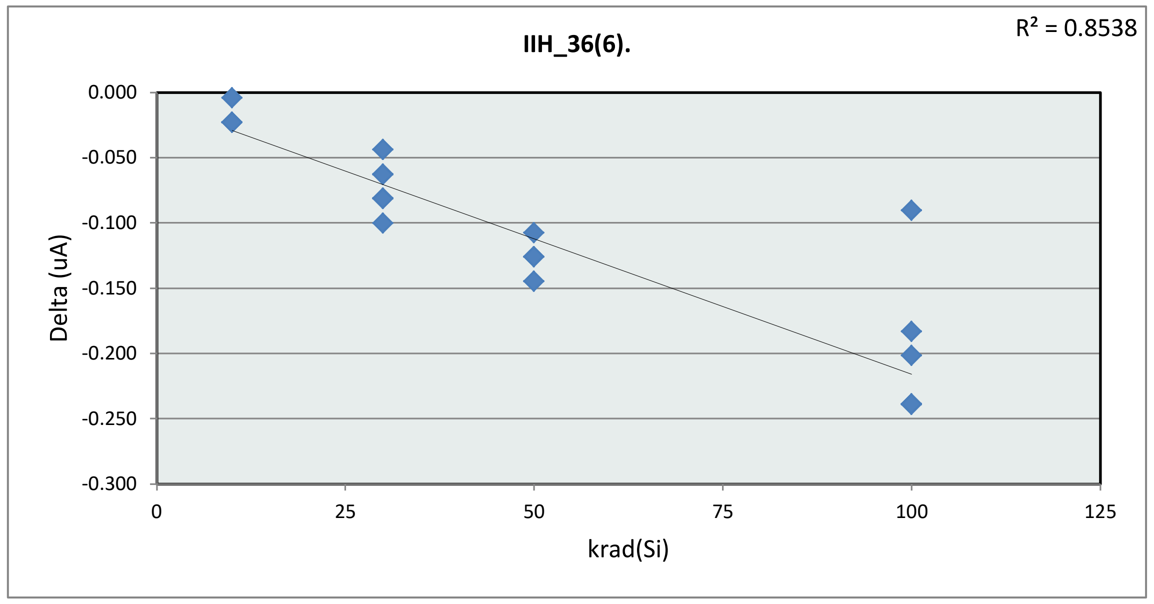
	IIH_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.974	3.024	3.048	3.121
Average	3.029	3.094	3.125	3.170
Max	3.104	3.173	3.197	3.215
UL	25.000	25.000	25.000	25.000



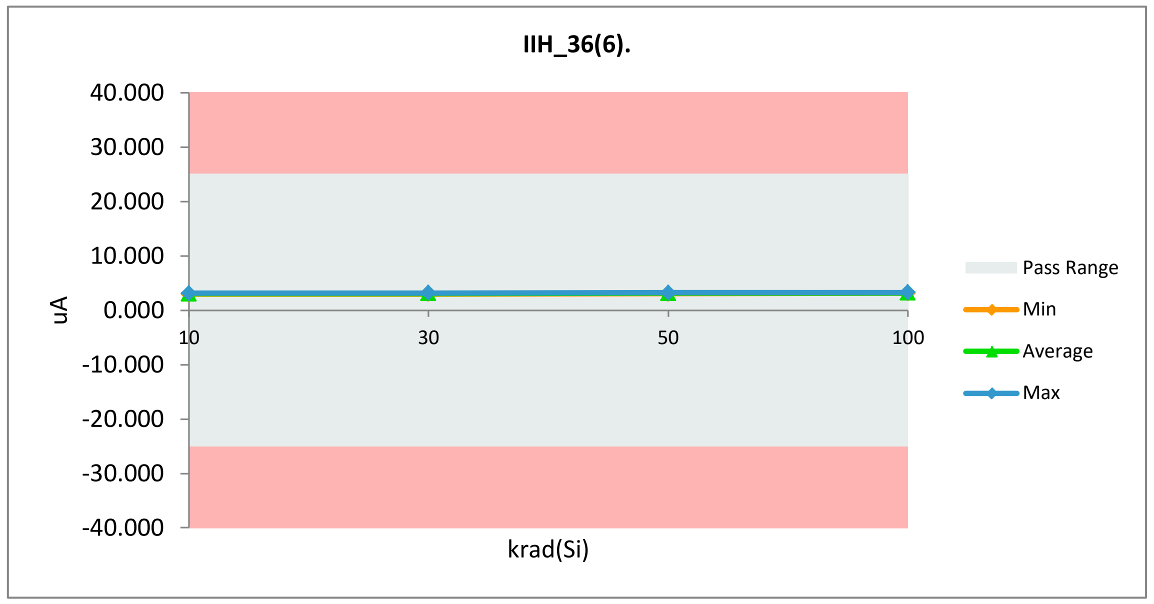
LDR Biased TID Report
SN55LVCP22A-SP

	IIH_36(6).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	2.940	2.963	-0.023
10	5	2.922	2.944	-0.023
10	7	3.070	3.075	-0.004
10	11	2.996	3.019	-0.023
10	15	3.033	3.056	-0.023
10	20	3.126	3.149	-0.023
10	21	3.033	3.056	-0.023
10	24	2.959	2.982	-0.023
30	1	2.940	3.003	-0.063
30	5	2.922	3.003	-0.081
30	7	3.070	3.114	-0.044
30	11	2.996	3.096	-0.100
30	15	3.033	3.096	-0.063
30	20	3.126	3.207	-0.081
30	21	3.033	3.077	-0.044
30	24	2.959	3.040	-0.081
50	1	2.940	3.066	-0.126
50	5	2.922	3.029	-0.108
50	7	3.070	3.196	-0.126
50	11	2.996	3.122	-0.126
50	15	3.033	3.178	-0.145
50	20	3.126	3.252	-0.126
50	21	3.033	3.159	-0.126
50	24	2.959	3.103	-0.145
100	3	2.940	3.179	-0.239
100	8	2.940	3.179	-0.239
100	12	2.959	3.142	-0.183
100	13	2.996	3.235	-0.239
100	16	3.014	3.216	-0.202
100	17	3.033	3.272	-0.239
100	18	3.107	3.198	-0.091
100	19	2.940	3.179	-0.239
	Max	3.126	3.272	-0.004
	Average	3.005	3.112	-0.107
	Min	2.922	2.944	-0.239
	Std Dev	0.064	0.088	0.076



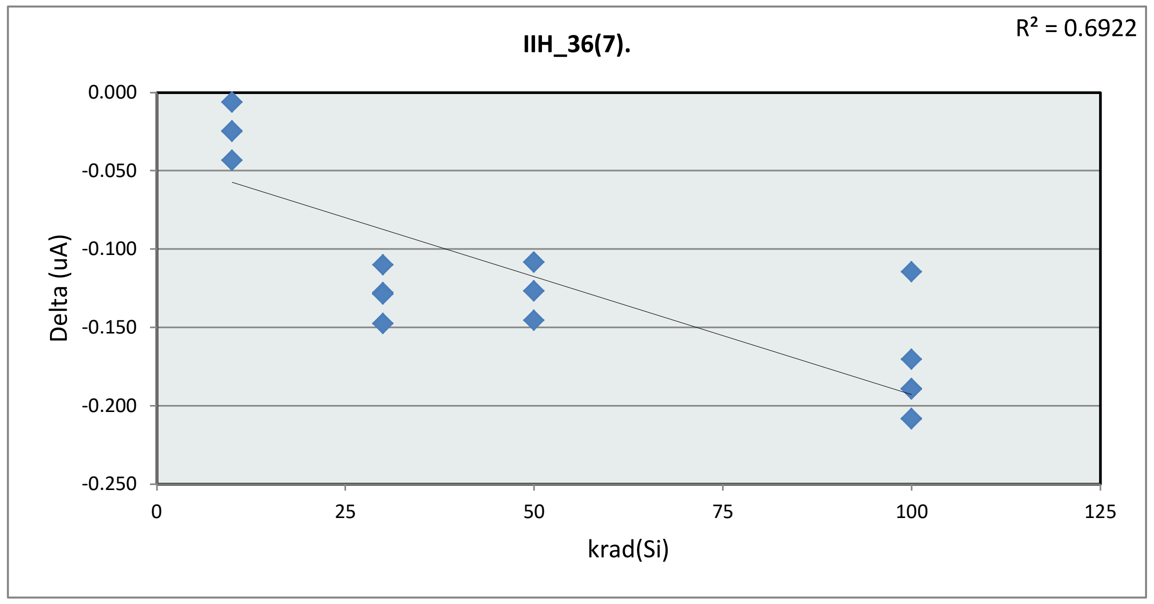
	IIH_36(6).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.944	3.003	3.029	3.142
Average	3.030	3.080	3.138	3.200
Max	3.149	3.207	3.252	3.272
UL	25.000	25.000	25.000	25.000



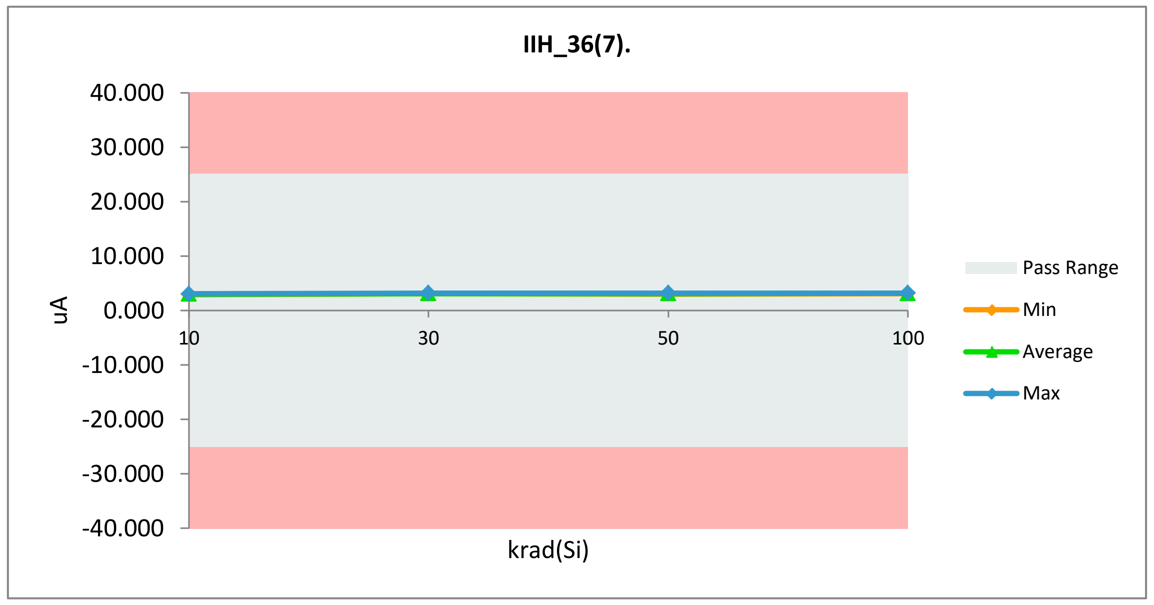
LDR Biased TID Report
SN55LVCP22A-SP

	IIH_36(7).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	2.958	2.982	-0.025
10	5	2.920	2.964	-0.043
10	7	3.013	3.057	-0.043
10	11	2.995	3.001	-0.006
10	15	3.088	3.094	-0.006
10	20	3.069	3.094	-0.025
10	21	3.013	3.038	-0.025
10	24	2.976	2.982	-0.006
30	1	2.958	3.086	-0.128
30	5	2.920	3.068	-0.148
30	7	3.013	3.161	-0.148
30	11	2.995	3.105	-0.110
30	15	3.088	3.216	-0.128
30	20	3.069	3.198	-0.129
30	21	3.013	3.142	-0.128
30	24	2.976	3.105	-0.129
50	1	2.958	3.085	-0.127
50	5	2.920	3.029	-0.108
50	7	3.013	3.140	-0.127
50	11	2.995	3.122	-0.127
50	15	3.088	3.196	-0.108
50	20	3.069	3.215	-0.146
50	21	3.013	3.122	-0.108
50	24	2.976	3.085	-0.108
100	3	2.939	3.128	-0.189
100	8	2.958	3.166	-0.208
100	12	2.958	3.147	-0.189
100	13	2.995	3.203	-0.208
100	16	3.051	3.240	-0.189
100	17	3.013	3.203	-0.190
100	18	3.069	3.184	-0.115
100	19	2.958	3.128	-0.170
	Max	3.088	3.240	-0.006
	Average	3.001	3.115	-0.114
	Min	2.920	2.964	-0.208
	Std Dev	0.051	0.074	0.061

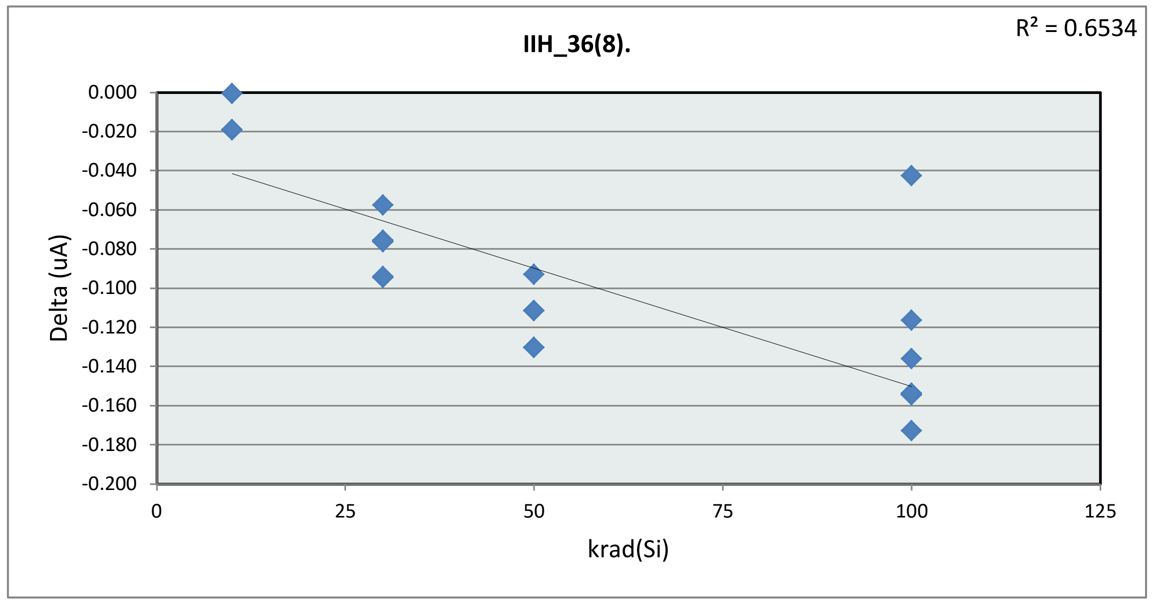


	IIH_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.964	3.068	3.029	3.128
Average	3.027	3.135	3.124	3.175
Max	3.094	3.216	3.215	3.240
UL	25.000	25.000	25.000	25.000

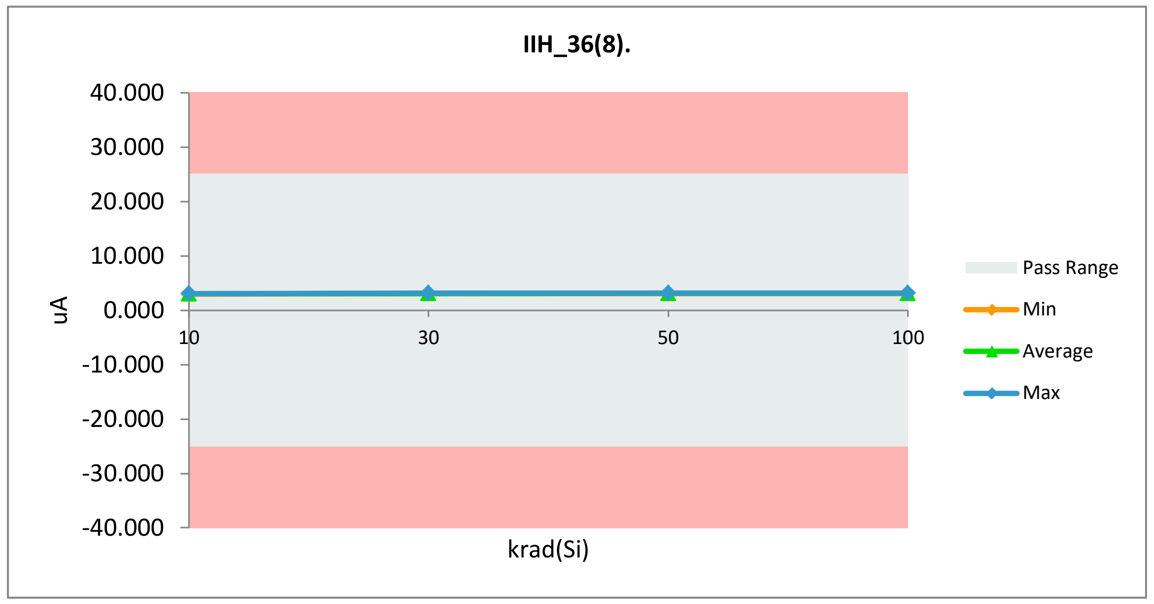


LDR Biased TID Report
SN55LVCP22A-SP

		IIH_36(8).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	2.943	2.962	-0.019
10	5	2.943	2.962	-0.019
10	7	3.018	3.037	-0.019
10	11	2.999	3.018	-0.019
10	15	3.092	3.111	-0.019
10	20	3.074	3.093	-0.019
10	21	3.018	3.037	-0.019
10	24	2.981	2.981	-0.001
30	1	2.943	3.038	-0.095
30	5	2.943	3.019	-0.076
30	7	3.018	3.112	-0.094
30	11	2.999	3.075	-0.076
30	15	3.092	3.168	-0.076
30	20	3.074	3.150	-0.076
30	21	3.018	3.094	-0.076
30	24	2.981	3.038	-0.057
50	1	2.943	3.074	-0.130
50	5	2.943	3.036	-0.093
50	7	3.018	3.148	-0.130
50	11	2.999	3.111	-0.112
50	15	3.092	3.204	-0.112
50	20	3.074	3.204	-0.130
50	21	3.018	3.129	-0.112
50	24	2.981	3.092	-0.112
100	3	2.943	3.097	-0.154
100	8	2.981	3.135	-0.154
100	12	2.981	3.097	-0.116
100	13	2.999	3.172	-0.173
100	16	3.055	3.191	-0.136
100	17	3.018	3.172	-0.154
100	18	3.092	3.135	-0.043
100	19	2.943	3.097	-0.154
	Max	3.092	3.204	-0.001
	Average	3.007	3.093	-0.087
	Min	2.943	2.962	-0.173
	Std Dev	0.051	0.067	0.051

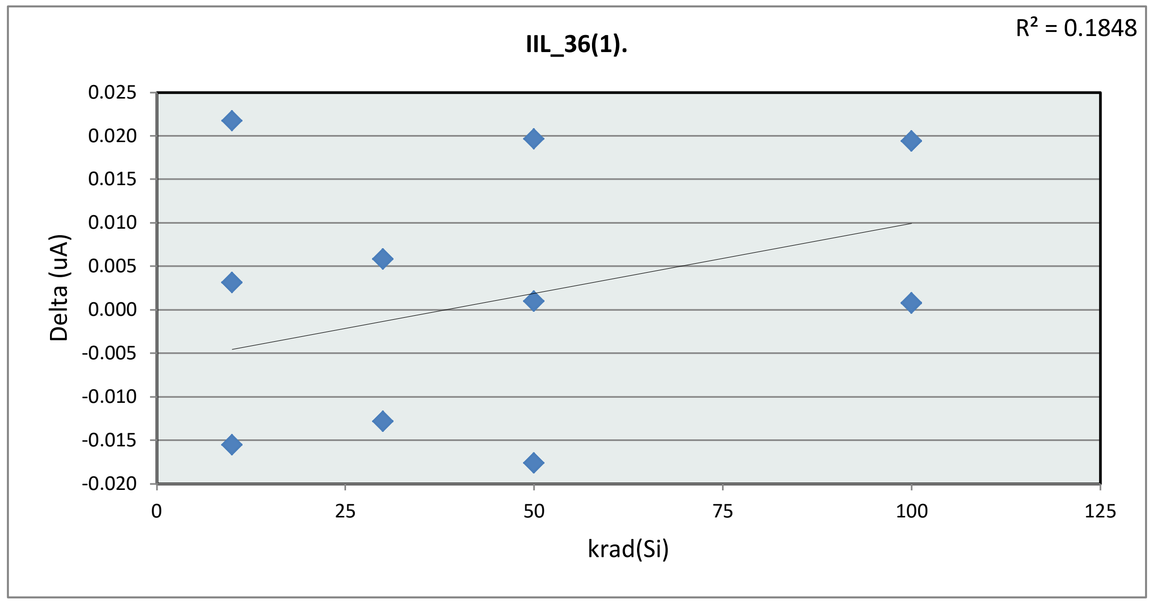


	IIH_36(8).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.962	3.019	3.036	3.097
Average	3.025	3.087	3.125	3.137
Max	3.111	3.168	3.204	3.191
UL	25.000	25.000	25.000	25.000

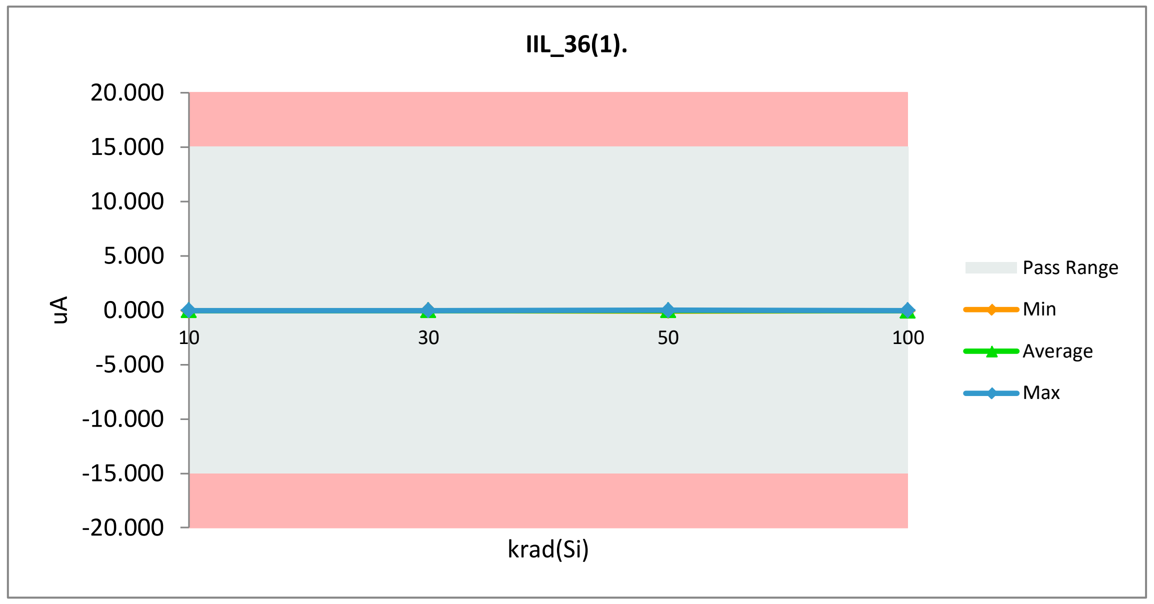


LDR Biased TID Report
SN55LVCP22A-SP

		IIL_36(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.023	-0.026	0.003
10	5	-0.023	-0.026	0.003
10	7	-0.023	-0.026	0.003
10	11	-0.042	-0.026	-0.016
10	15	-0.042	-0.026	-0.016
10	20	-0.023	-0.026	0.003
10	21	-0.042	-0.026	-0.016
10	24	-0.023	-0.045	0.022
30	1	-0.023	-0.029	0.006
30	5	-0.023	-0.029	0.006
30	7	-0.023	-0.029	0.006
30	11	-0.042	-0.029	-0.013
30	15	-0.042	-0.029	-0.013
30	20	-0.023	-0.029	0.006
30	21	-0.042	-0.029	-0.013
30	24	-0.023	-0.029	0.006
50	1	-0.023	-0.006	-0.018
50	5	-0.023	-0.024	0.001
50	7	-0.023	-0.024	0.001
50	11	-0.042	-0.061	0.020
50	15	-0.042	-0.024	-0.018
50	20	-0.023	-0.024	0.001
50	21	-0.042	-0.024	-0.018
50	24	-0.023	-0.024	0.001
100	3	-0.023	-0.024	0.001
100	8	-0.023	-0.043	0.019
100	12	-0.023	-0.043	0.019
100	13	-0.023	-0.043	0.019
100	16	-0.023	-0.043	0.019
100	17	-0.023	-0.043	0.019
100	18	-0.042	-0.043	0.001
100	19	-0.023	-0.024	0.001
	Max	-0.023	-0.006	0.022
	Average	-0.029	-0.030	0.002
	Min	-0.042	-0.061	-0.018
	Std Dev	0.009	0.010	0.013



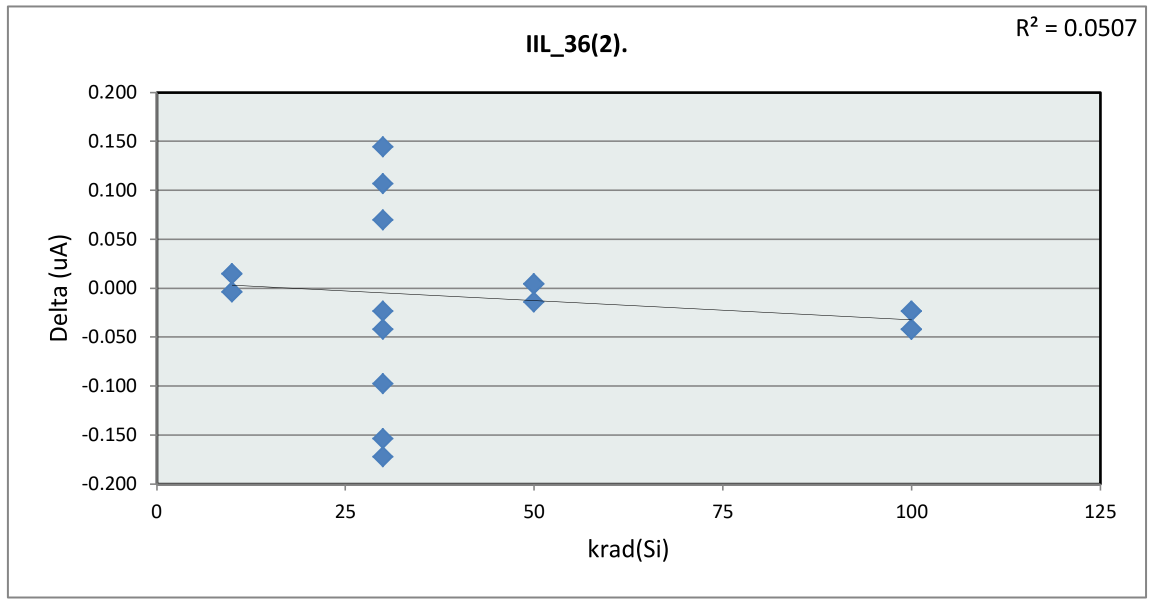
	IIL_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.045	-0.029	-0.061	-0.043
Average	-0.029	-0.029	-0.026	-0.038
Max	-0.026	-0.029	-0.006	-0.024
UL	15.000	15.000	15.000	15.000



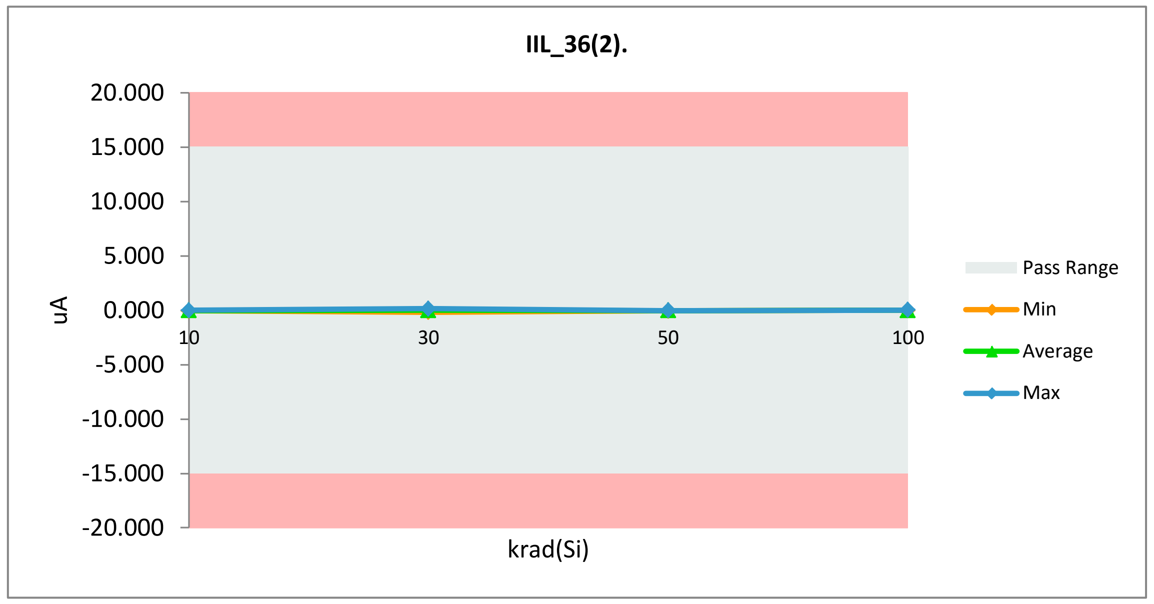
LDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(2).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.034	-0.030	-0.004
10	5	-0.034	-0.049	0.015
10	7	-0.016	-0.012	-0.004
10	11	-0.016	-0.030	0.015
10	15	-0.016	-0.012	-0.004
10	20	-0.016	-0.030	0.015
10	21	-0.016	-0.030	0.015
10	24	-0.016	-0.030	0.015
30	1	-0.034	0.008	-0.042
30	5	-0.034	0.119	-0.154
30	7	-0.016	-0.160	0.144
30	11	-0.016	-0.122	0.107
30	15	-0.016	0.082	-0.098
30	20	-0.016	0.157	-0.172
30	21	-0.016	0.008	-0.023
30	24	-0.016	-0.085	0.070
50	1	-0.034	-0.020	-0.014
50	5	-0.034	-0.038	0.004
50	7	-0.016	-0.020	0.004
50	11	-0.016	-0.020	0.004
50	15	-0.016	-0.020	0.004
50	20	-0.016	-0.020	0.004
50	21	-0.016	-0.020	0.004
50	24	-0.016	-0.020	0.004
100	3	-0.034	0.008	-0.042
100	8	-0.034	0.008	-0.042
100	12	-0.016	0.027	-0.042
100	13	-0.034	0.008	-0.042
100	16	-0.016	0.008	-0.024
100	17	-0.034	0.008	-0.042
100	18	-0.016	0.008	-0.024
100	19	-0.016	0.008	-0.024
	Max	-0.016	0.157	0.144
	Average	-0.021	-0.010	-0.012
	Min	-0.034	-0.160	-0.172
	Std Dev	0.009	0.058	0.060

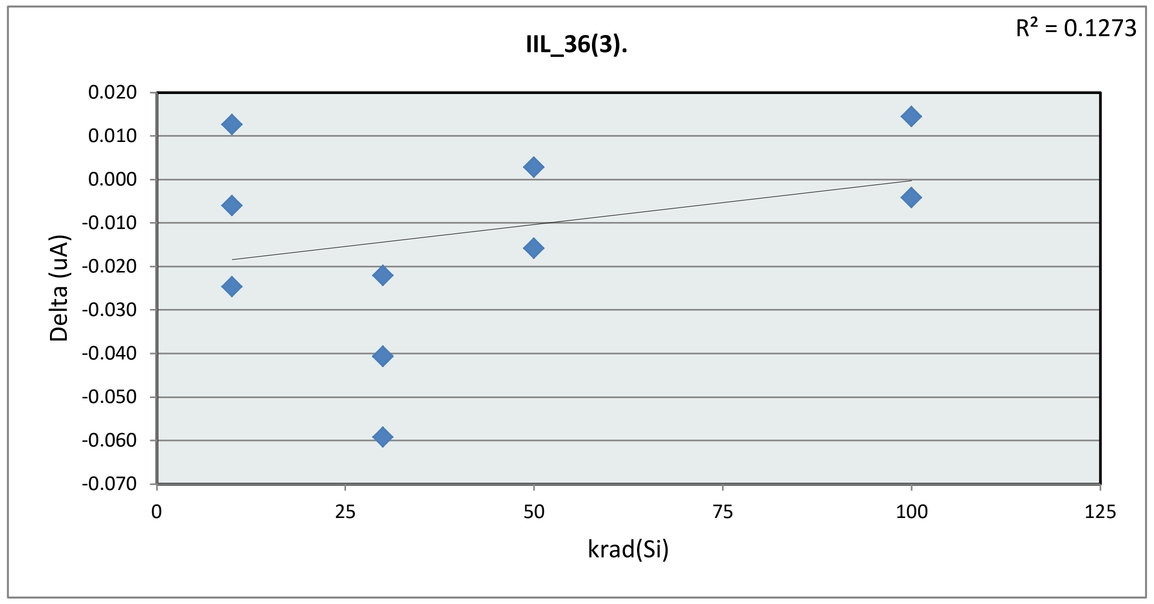


	IIL_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.049	-0.160	-0.038	0.008
Average	-0.028	0.001	-0.022	0.010
Max	-0.012	0.157	-0.020	0.027
UL	15.000	15.000	15.000	15.000

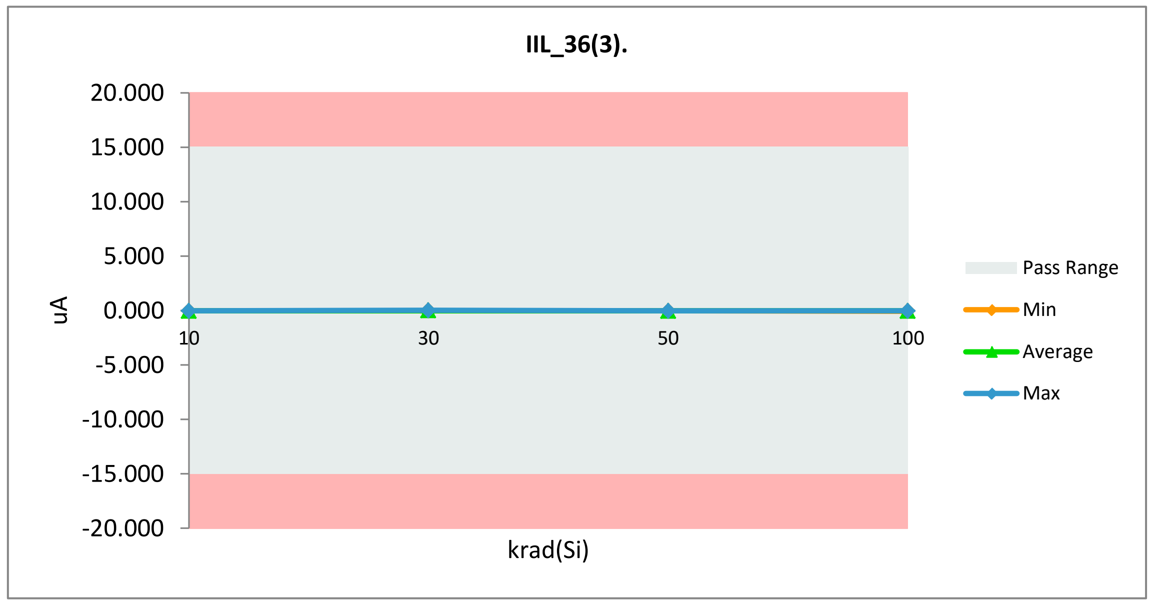


LDR Biased TID Report
SN55LVCP22A-SP

		IIL_36(3).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.041	-0.035	-0.006
10	5	-0.041	-0.017	-0.025
10	7	-0.041	-0.017	-0.025
10	11	-0.041	-0.035	-0.006
10	15	-0.023	-0.035	0.013
10	20	-0.023	-0.017	-0.006
10	21	-0.023	-0.035	0.013
10	24	-0.023	-0.035	0.013
30	1	-0.041	0.000	-0.041
30	5	-0.041	0.000	-0.041
30	7	-0.041	0.000	-0.041
30	11	-0.041	0.018	-0.059
30	15	-0.023	0.000	-0.022
30	20	-0.023	0.000	-0.022
30	21	-0.023	0.018	-0.041
30	24	-0.023	0.000	-0.022
50	1	-0.041	-0.025	-0.016
50	5	-0.041	-0.025	-0.016
50	7	-0.041	-0.025	-0.016
50	11	-0.041	-0.025	-0.016
50	15	-0.023	-0.025	0.003
50	20	-0.023	-0.025	0.003
50	21	-0.023	-0.025	0.003
50	24	-0.023	-0.025	0.003
100	3	-0.023	-0.037	0.014
100	8	-0.041	-0.037	-0.004
100	12	-0.023	-0.018	-0.004
100	13	-0.023	-0.018	-0.004
100	16	-0.041	-0.056	0.014
100	17	-0.023	-0.018	-0.004
100	18	-0.023	-0.037	0.014
100	19	-0.023	-0.018	-0.004
	Max	-0.023	0.018	0.014
	Average	-0.031	-0.020	-0.011
	Min	-0.041	-0.056	-0.059
	Std Dev	0.009	0.017	0.019

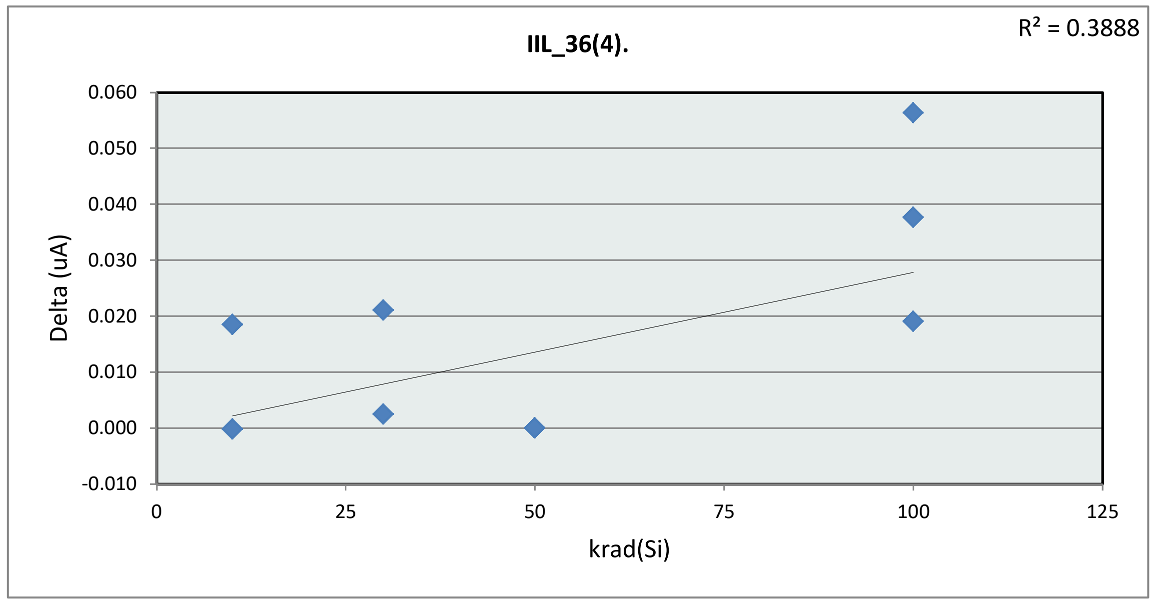


	IIL_36(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.035	0.000	-0.025	-0.056
Average	-0.028	0.004	-0.025	-0.030
Max	-0.017	0.018	-0.025	-0.018
UL	15.000	15.000	15.000	15.000

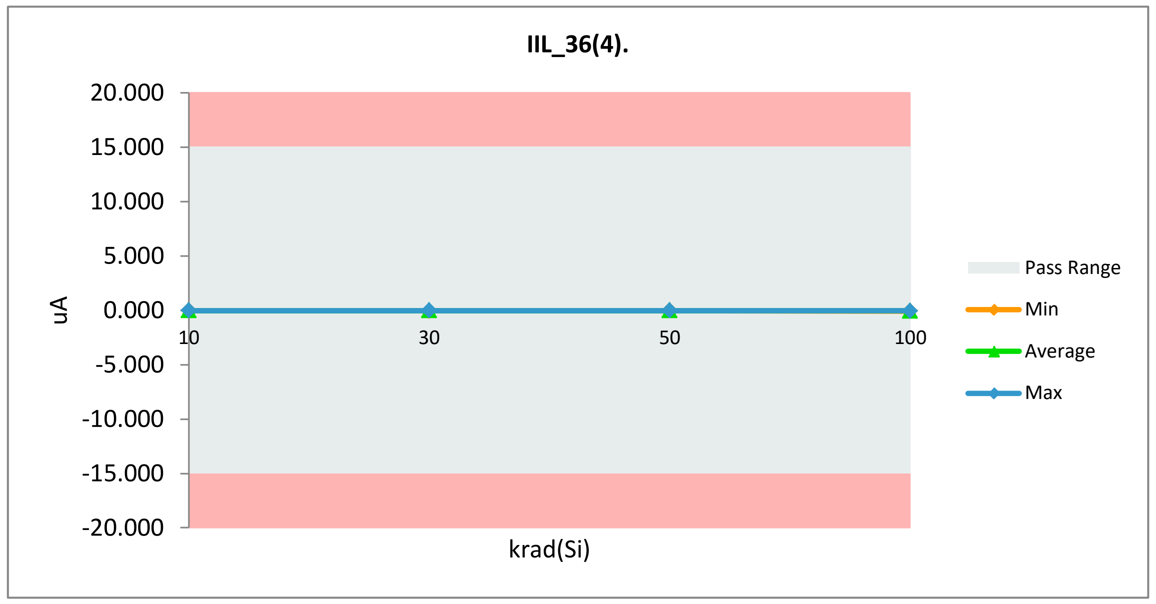


LDR Biased TID Report
SN55LVCP22A-SP

		IIL_36(4).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.017	-0.017	0.000
10	5	-0.017	-0.017	0.000
10	7	-0.017	-0.036	0.018
10	11	-0.017	-0.017	0.000
10	15	-0.017	-0.036	0.018
10	20	-0.017	-0.017	0.000
10	21	-0.017	-0.017	0.000
10	24	-0.017	-0.036	0.018
30	1	-0.017	-0.039	0.021
30	5	-0.017	-0.020	0.002
30	7	-0.017	-0.020	0.002
30	11	-0.017	-0.039	0.021
30	15	-0.017	-0.039	0.021
30	20	-0.017	-0.020	0.002
30	21	-0.017	-0.039	0.021
30	24	-0.017	-0.020	0.002
50	1	-0.017	-0.017	0.000
50	5	-0.017	-0.017	0.000
50	7	-0.017	-0.017	0.000
50	11	-0.017	-0.017	0.000
50	15	-0.017	-0.017	0.000
50	20	-0.017	-0.017	0.000
50	21	-0.017	-0.017	0.000
50	24	-0.017	-0.017	0.000
100	3	-0.017	-0.074	0.056
100	8	-0.017	-0.055	0.038
100	12	-0.017	-0.055	0.038
100	13	-0.017	-0.055	0.038
100	16	-0.036	-0.055	0.019
100	17	-0.036	-0.055	0.019
100	18	-0.036	-0.055	0.019
100	19	-0.017	-0.055	0.038
	Max	-0.017	-0.017	0.056
	Average	-0.019	-0.032	0.013
	Min	-0.036	-0.074	0.000
	Std Dev	0.006	0.017	0.015



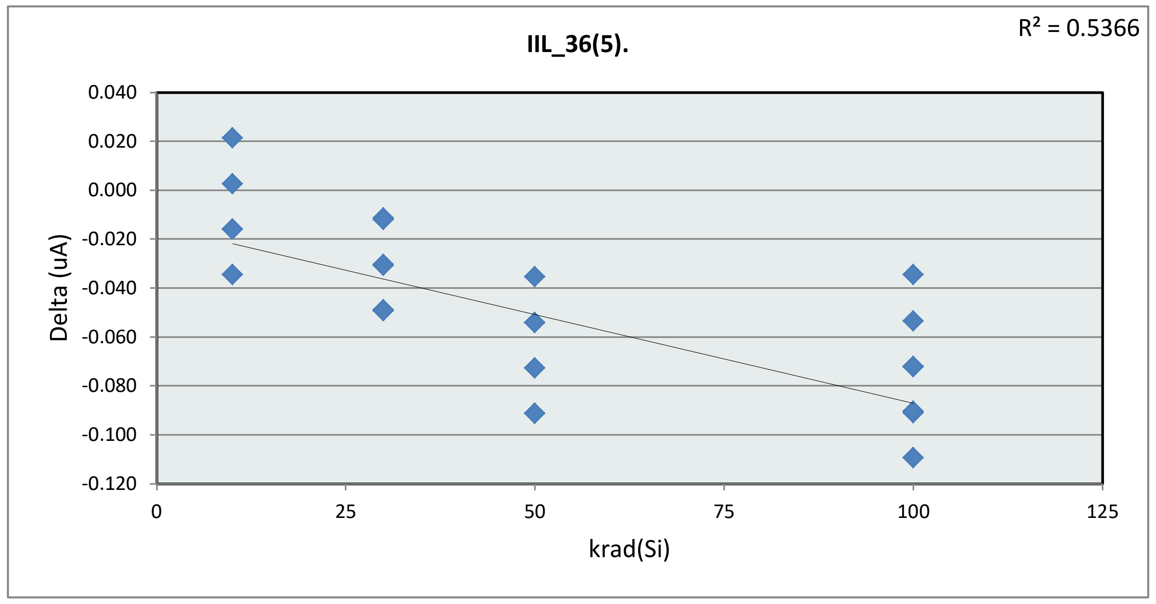
IIL_36(4).				
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.036	-0.039	-0.017	-0.074
Average	-0.024	-0.029	-0.017	-0.057
Max	-0.017	-0.020	-0.017	-0.055
UL	15.000	15.000	15.000	15.000



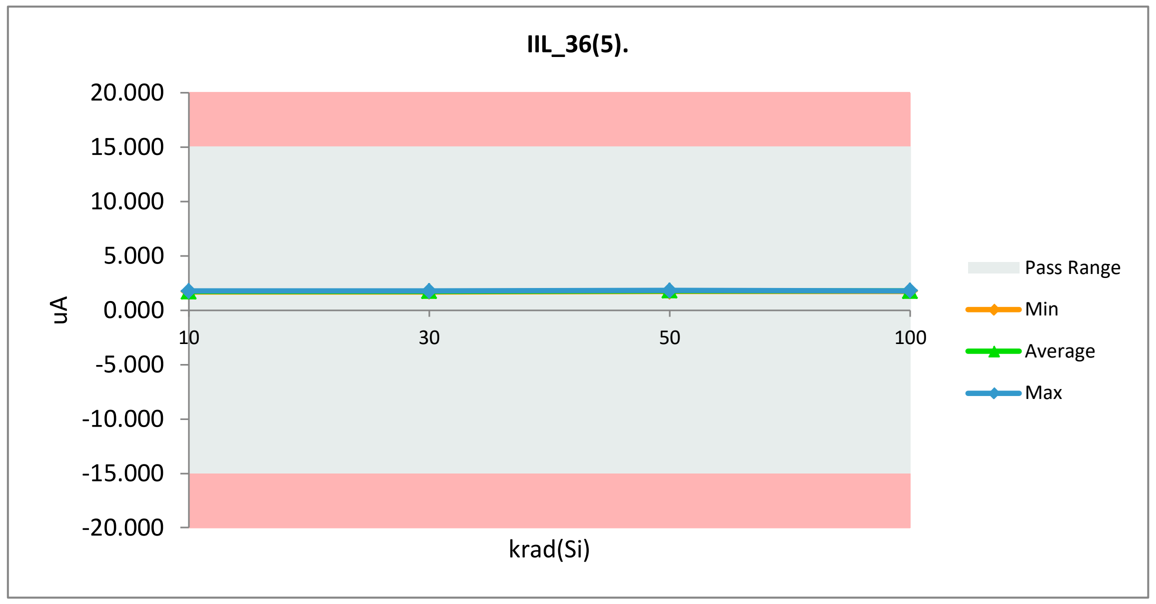
LDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(5).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.672	1.707	-0.035
10	5	1.691	1.688	0.003
10	7	1.709	1.725	-0.016
10	11	1.691	1.725	-0.035
10	15	1.765	1.744	0.021
10	20	1.746	1.762	-0.016
10	21	1.709	1.725	-0.016
10	24	1.691	1.707	-0.016
30	1	1.672	1.721	-0.049
30	5	1.691	1.702	-0.011
30	7	1.709	1.758	-0.049
30	11	1.691	1.740	-0.049
30	15	1.765	1.777	-0.012
30	20	1.746	1.777	-0.031
30	21	1.709	1.740	-0.031
30	24	1.691	1.721	-0.030
50	1	1.672	1.763	-0.091
50	5	1.691	1.726	-0.035
50	7	1.709	1.801	-0.091
50	11	1.691	1.782	-0.091
50	15	1.765	1.819	-0.054
50	20	1.746	1.819	-0.073
50	21	1.709	1.763	-0.054
50	24	1.691	1.763	-0.073
100	3	1.672	1.763	-0.091
100	8	1.691	1.781	-0.090
100	12	1.691	1.744	-0.053
100	13	1.691	1.800	-0.109
100	16	1.728	1.800	-0.072
100	17	1.691	1.800	-0.109
100	18	1.746	1.781	-0.035
100	19	1.672	1.744	-0.072
	Max	1.765	1.819	0.021
	Average	1.706	1.755	-0.049
	Min	1.672	1.688	-0.109
	Std Dev	0.029	0.035	0.034



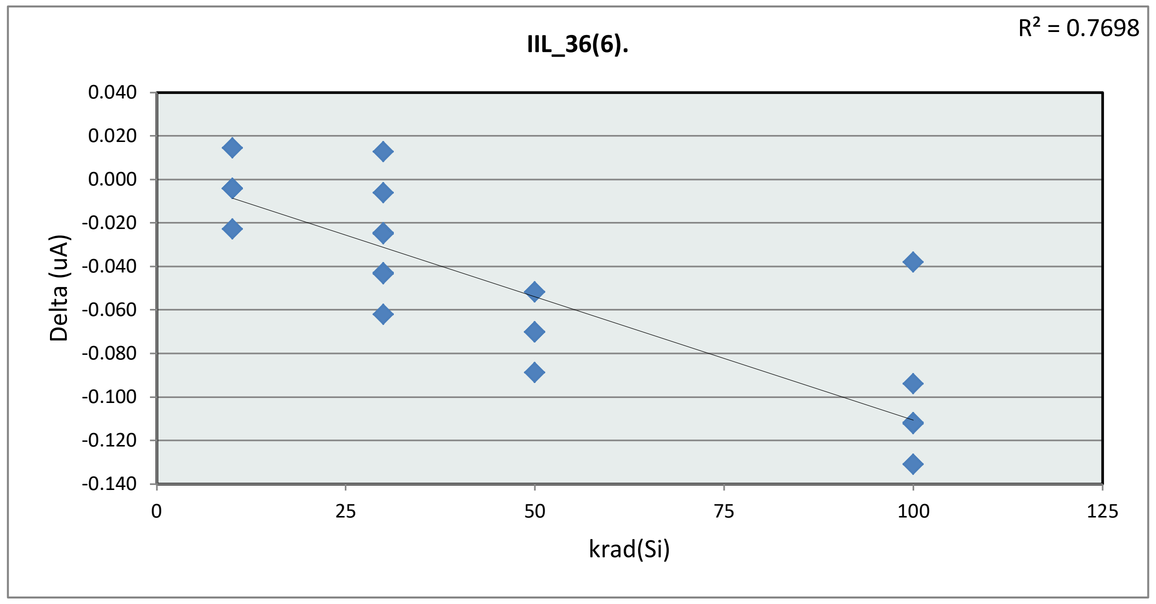
	IIL_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.688	1.702	1.726	1.744
Average	1.723	1.742	1.780	1.777
Max	1.762	1.777	1.819	1.800
UL	15.000	15.000	15.000	15.000



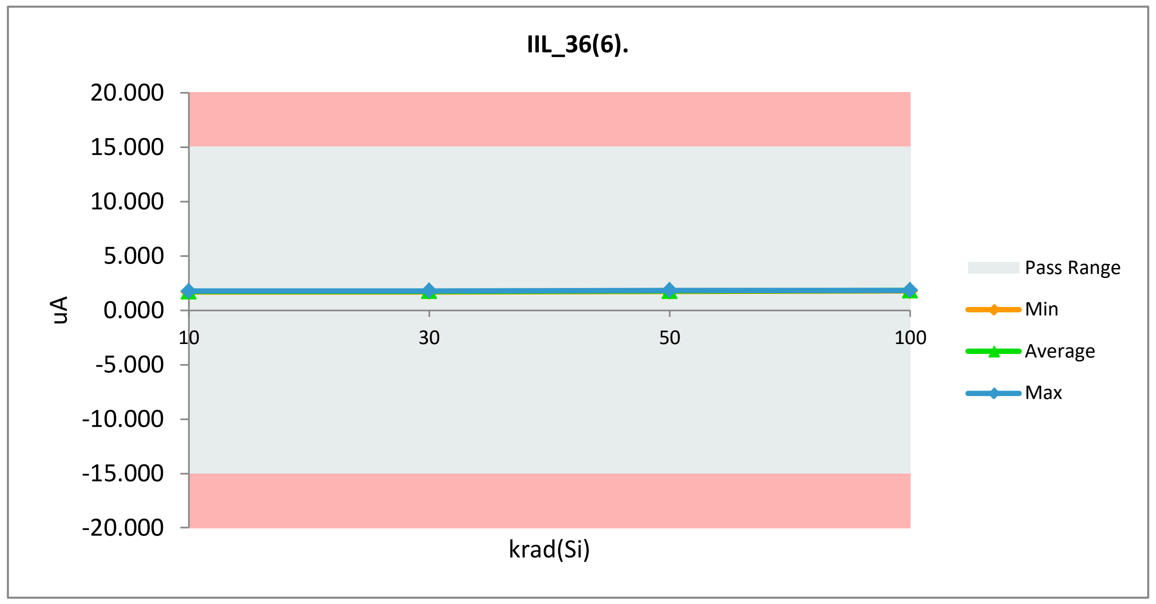
LDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(6).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.676	1.680	-0.004
10	5	1.657	1.662	-0.004
10	7	1.732	1.736	-0.004
10	11	1.695	1.717	-0.023
10	15	1.713	1.717	-0.004
10	20	1.769	1.773	-0.004
10	21	1.732	1.736	-0.004
10	24	1.695	1.680	0.014
30	1	1.676	1.719	-0.043
30	5	1.657	1.682	-0.025
30	7	1.732	1.794	-0.062
30	11	1.695	1.738	-0.043
30	15	1.713	1.738	-0.025
30	20	1.769	1.794	-0.025
30	21	1.732	1.738	-0.006
30	24	1.695	1.682	0.013
50	1	1.676	1.746	-0.070
50	5	1.657	1.709	-0.052
50	7	1.732	1.802	-0.070
50	11	1.695	1.765	-0.070
50	15	1.713	1.802	-0.089
50	20	1.769	1.839	-0.070
50	21	1.732	1.784	-0.052
50	24	1.695	1.765	-0.070
100	3	1.676	1.807	-0.131
100	8	1.676	1.788	-0.112
100	12	1.676	1.770	-0.094
100	13	1.713	1.825	-0.112
100	16	1.695	1.807	-0.112
100	17	1.732	1.844	-0.112
100	18	1.769	1.807	-0.038
100	19	1.676	1.807	-0.131
	Max	1.769	1.844	0.014
	Average	1.707	1.758	-0.051
	Min	1.657	1.662	-0.131
	Std Dev	0.034	0.050	0.044



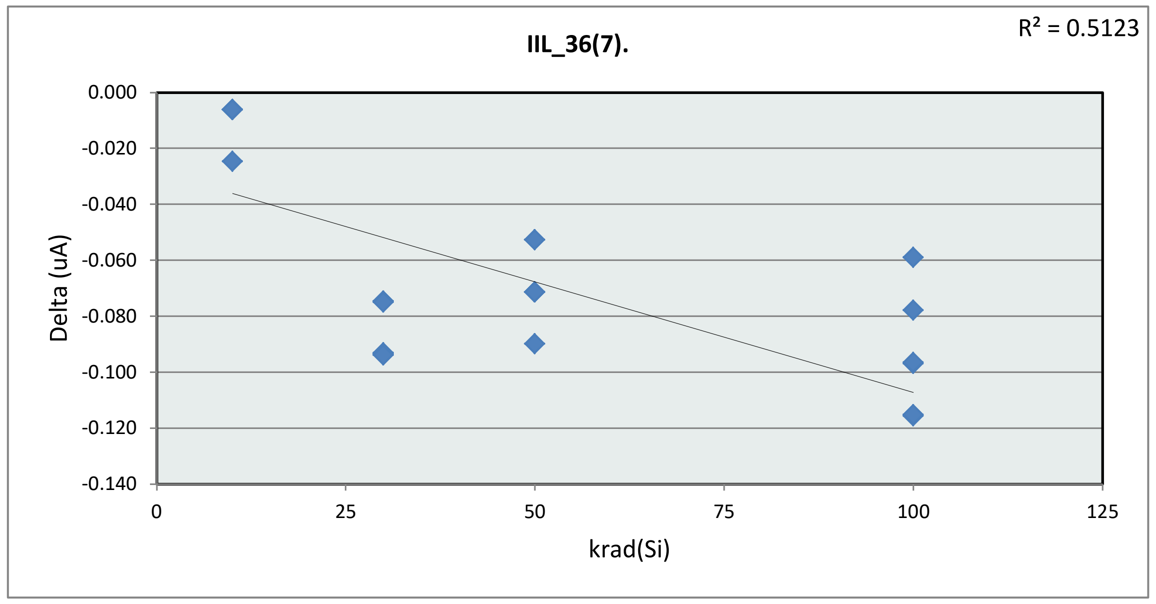
	IIL_36(6).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.662	1.682	1.709	1.770
Average	1.713	1.736	1.777	1.807
Max	1.773	1.794	1.839	1.844
UL	15.000	15.000	15.000	15.000



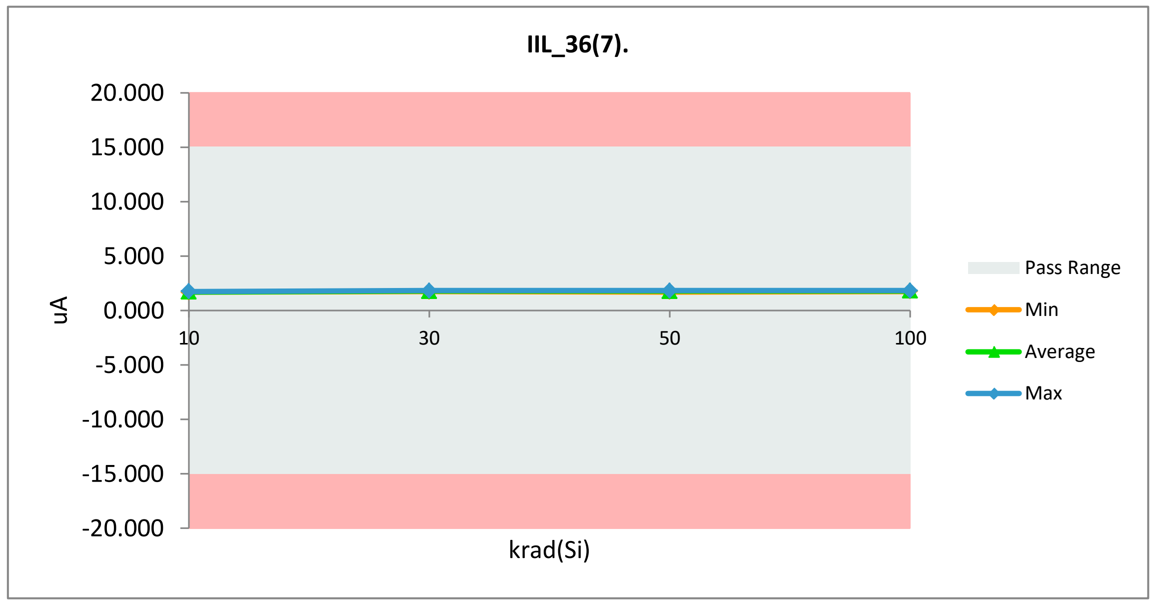
LDR Biased TID Report
SN55LVCP22A-SP

	IIL_36(7).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.672	1.697	-0.025
10	5	1.672	1.679	-0.006
10	7	1.728	1.734	-0.006
10	11	1.691	1.697	-0.006
10	15	1.747	1.753	-0.006
10	20	1.747	1.753	-0.006
10	21	1.710	1.716	-0.006
10	24	1.691	1.697	-0.006
30	1	1.672	1.766	-0.094
30	5	1.672	1.747	-0.075
30	7	1.728	1.803	-0.075
30	11	1.691	1.785	-0.094
30	15	1.747	1.840	-0.093
30	20	1.747	1.822	-0.075
30	21	1.710	1.803	-0.093
30	24	1.691	1.785	-0.094
50	1	1.672	1.744	-0.071
50	5	1.672	1.725	-0.053
50	7	1.728	1.781	-0.053
50	11	1.691	1.762	-0.071
50	15	1.747	1.818	-0.071
50	20	1.747	1.837	-0.090
50	21	1.710	1.781	-0.071
50	24	1.691	1.762	-0.071
100	3	1.672	1.788	-0.116
100	8	1.691	1.788	-0.097
100	12	1.691	1.769	-0.078
100	13	1.710	1.825	-0.115
100	16	1.728	1.844	-0.116
100	17	1.710	1.825	-0.115
100	18	1.747	1.806	-0.059
100	19	1.672	1.769	-0.097
	Max	1.747	1.844	-0.006
	Average	1.706	1.772	-0.066
	Min	1.672	1.679	-0.116
	Std Dev	0.028	0.045	0.038

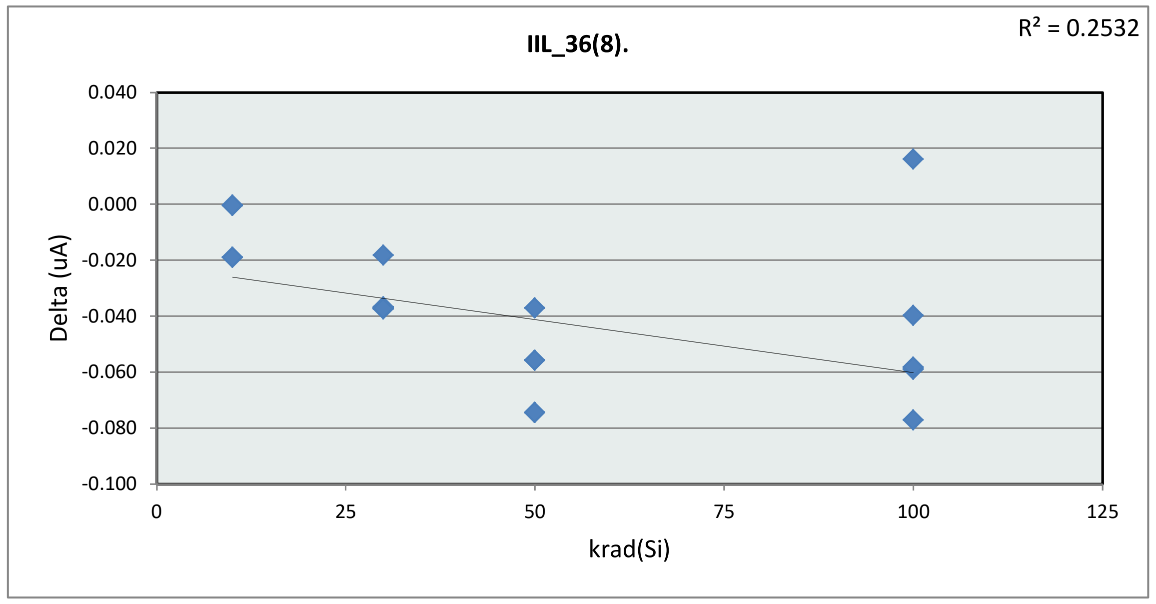


	IIL_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.679	1.747	1.725	1.769
Average	1.716	1.794	1.776	1.802
Max	1.753	1.840	1.837	1.844
UL	15.000	15.000	15.000	15.000

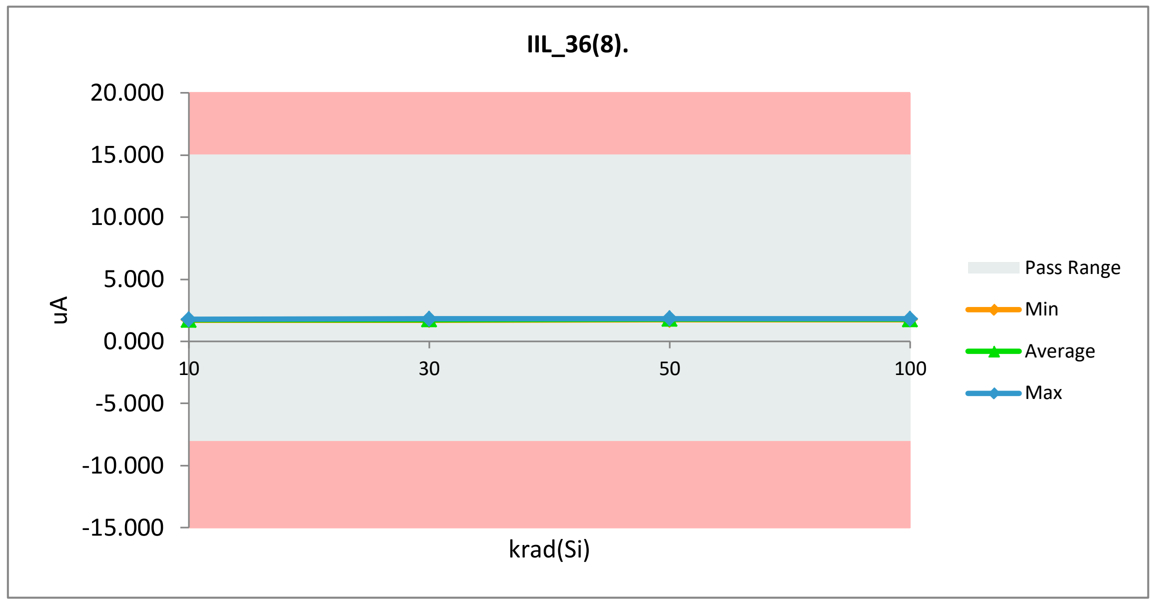


LDR Biased TID Report
SN55LVCP22A-SP

		IIL_36(8).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.696	1.715	-0.019
10	5	1.696	1.696	0.000
10	7	1.733	1.752	-0.019
10	11	1.714	1.733	-0.019
10	15	1.770	1.771	0.000
10	20	1.752	1.771	-0.019
10	21	1.733	1.733	0.000
10	24	1.696	1.715	-0.019
30	1	1.696	1.733	-0.037
30	5	1.696	1.714	-0.018
30	7	1.733	1.770	-0.037
30	11	1.714	1.751	-0.037
30	15	1.770	1.807	-0.037
30	20	1.752	1.789	-0.037
30	21	1.733	1.770	-0.037
30	24	1.696	1.733	-0.037
50	1	1.696	1.770	-0.074
50	5	1.696	1.733	-0.037
50	7	1.733	1.807	-0.074
50	11	1.714	1.789	-0.074
50	15	1.770	1.826	-0.056
50	20	1.752	1.826	-0.074
50	21	1.733	1.789	-0.056
50	24	1.696	1.770	-0.074
100	3	1.696	1.754	-0.058
100	8	1.714	1.773	-0.059
100	12	1.714	1.754	-0.040
100	13	1.733	1.792	-0.059
100	16	1.733	1.810	-0.077
100	17	1.733	1.792	-0.059
100	18	1.770	1.754	0.016
100	19	1.696	1.754	-0.058
	Max	1.770	1.826	0.016
	Average	1.724	1.764	-0.040
	Min	1.696	1.696	-0.077
	Std Dev	0.026	0.033	0.025

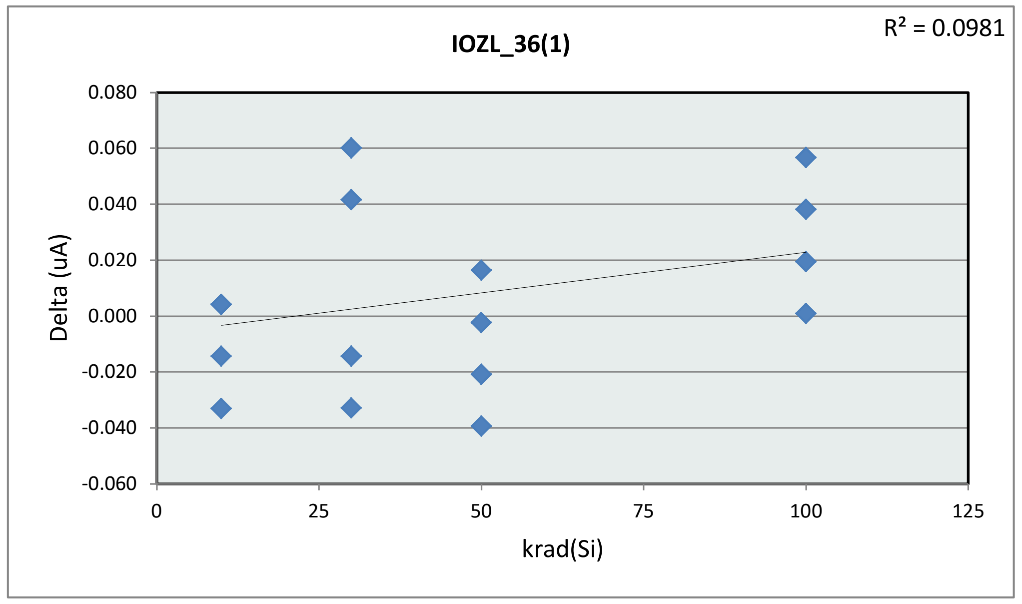


	IIL_36(8).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-8	uA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	1.696	1.714	1.733	1.754
Average	1.736	1.758	1.789	1.773
Max	1.771	1.807	1.826	1.810
UL	15.000	15.000	15.000	15.000

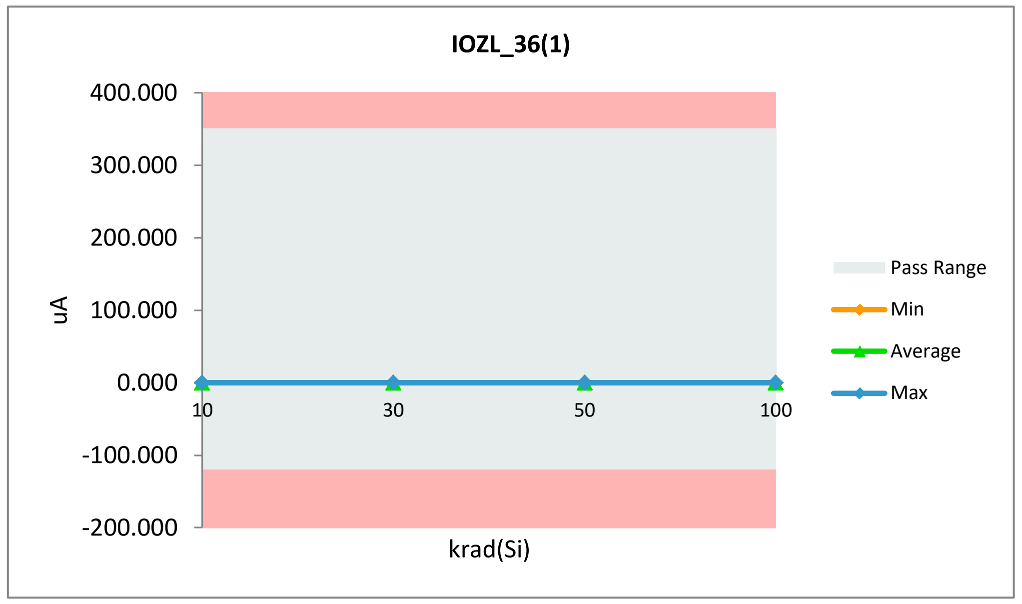


LDR Biased TID Report
SN55LVCP22A-SP

		IOZL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.003	-0.001	0.004
10	5	0.003	-0.001	0.004
10	7	-0.015	0.018	-0.033
10	11	0.003	-0.001	0.004
10	15	0.003	0.018	-0.014
10	20	-0.015	0.018	-0.033
10	21	-0.015	-0.019	0.004
10	24	0.003	-0.001	0.004
30	1	0.003	-0.057	0.060
30	5	0.003	-0.057	0.060
30	7	-0.015	0.018	-0.033
30	11	0.003	-0.057	0.060
30	15	0.003	0.018	-0.014
30	20	-0.015	-0.057	0.041
30	21	-0.015	-0.057	0.041
30	24	0.003	0.018	-0.014
50	1	0.003	0.006	-0.002
50	5	0.003	-0.013	0.016
50	7	-0.015	0.024	-0.039
50	11	0.003	0.024	-0.021
50	15	0.003	0.024	-0.021
50	20	-0.015	0.024	-0.039
50	21	-0.015	0.006	-0.021
50	24	0.003	0.006	-0.002
100	3	-0.015	-0.035	0.019
100	8	0.022	-0.035	0.057
100	12	-0.015	-0.016	0.001
100	13	0.022	-0.035	0.057
100	16	0.003	-0.035	0.038
100	17	0.003	-0.016	0.019
100	18	-0.015	-0.016	0.001
100	19	0.003	-0.035	0.038
	Max	0.022	0.024	0.060
	Average	-0.002	-0.010	0.008
	Min	-0.015	-0.057	-0.039
	Std Dev	0.011	0.028	0.032

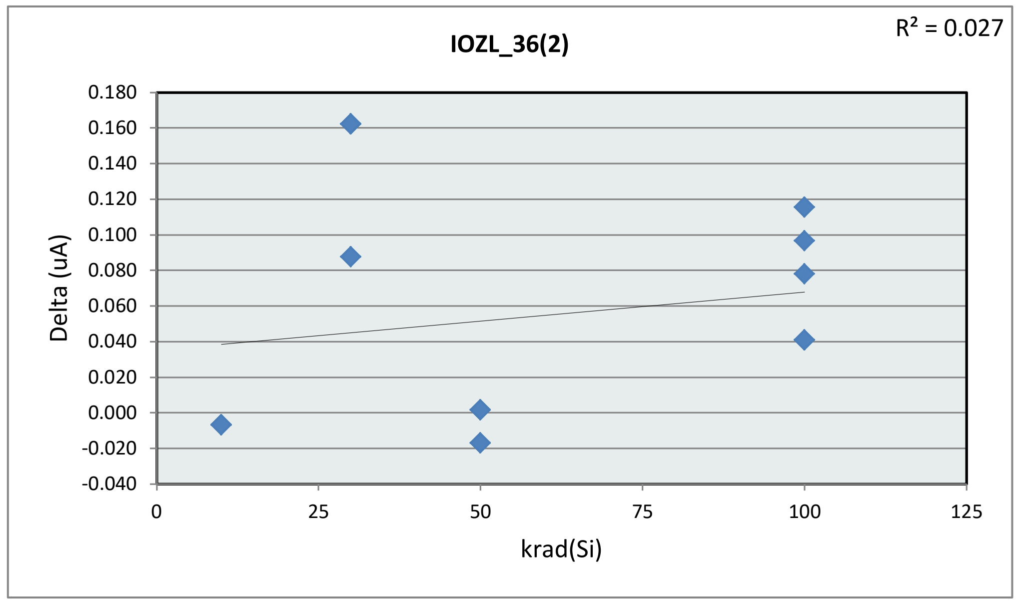


	IOZL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.019	-0.057	-0.013	-0.035
Average	0.004	-0.029	0.013	-0.028
Max	0.018	0.018	0.024	-0.016
UL	350.000	350.000	350.000	350.000

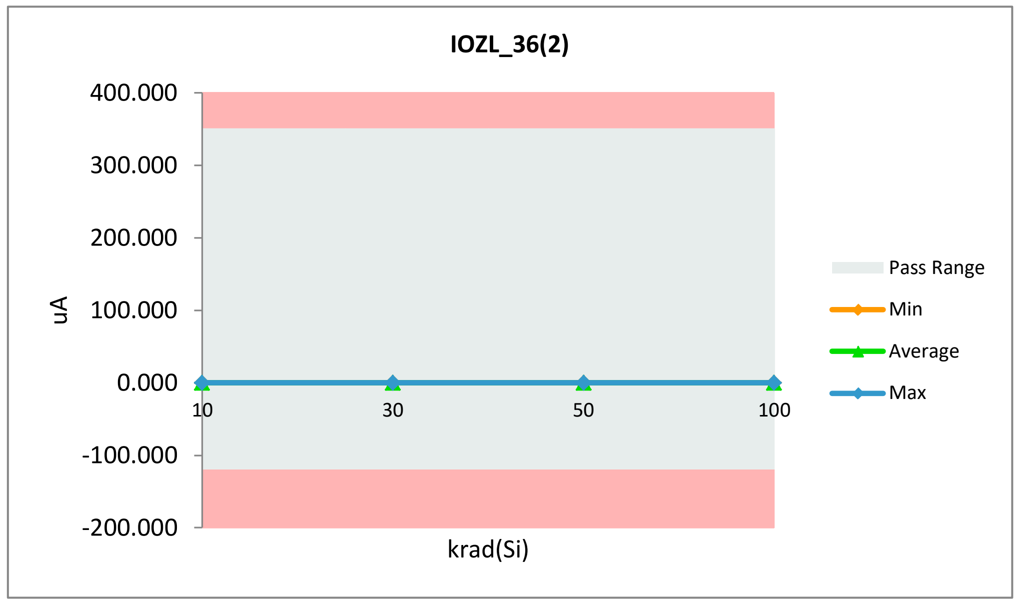


LDR Biased TID Report
SN55LVCP22A-SP

		IOZL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.005	0.001	-0.007
10	5	-0.005	0.001	-0.007
10	7	-0.005	0.001	-0.007
10	11	-0.005	0.001	-0.007
10	15	-0.005	0.001	-0.007
10	20	-0.005	0.001	-0.007
10	21	-0.005	0.001	-0.007
10	24	-0.005	0.001	-0.007
30	1	-0.005	-0.093	0.088
30	5	-0.005	-0.168	0.162
30	7	-0.005	-0.168	0.162
30	11	-0.005	-0.168	0.162
30	15	-0.005	-0.168	0.162
30	20	-0.005	-0.168	0.162
30	21	-0.005	-0.093	0.088
30	24	-0.005	-0.168	0.162
50	1	-0.005	-0.007	0.002
50	5	-0.005	-0.007	0.002
50	7	-0.005	-0.007	0.002
50	11	-0.005	-0.007	0.002
50	15	-0.005	0.012	-0.017
50	20	-0.005	0.012	-0.017
50	21	-0.005	-0.007	0.002
50	24	-0.005	0.012	-0.017
100	3	-0.005	-0.102	0.097
100	8	-0.005	-0.121	0.115
100	12	-0.005	-0.046	0.041
100	13	-0.005	-0.046	0.041
100	16	-0.005	-0.121	0.115
100	17	-0.005	-0.046	0.041
100	18	-0.005	-0.083	0.078
100	19	-0.005	-0.046	0.041
	Max	-0.005	0.012	0.162
	Average	-0.005	-0.056	0.051
	Min	-0.005	-0.168	-0.017
	Std Dev	0.000	0.067	0.067

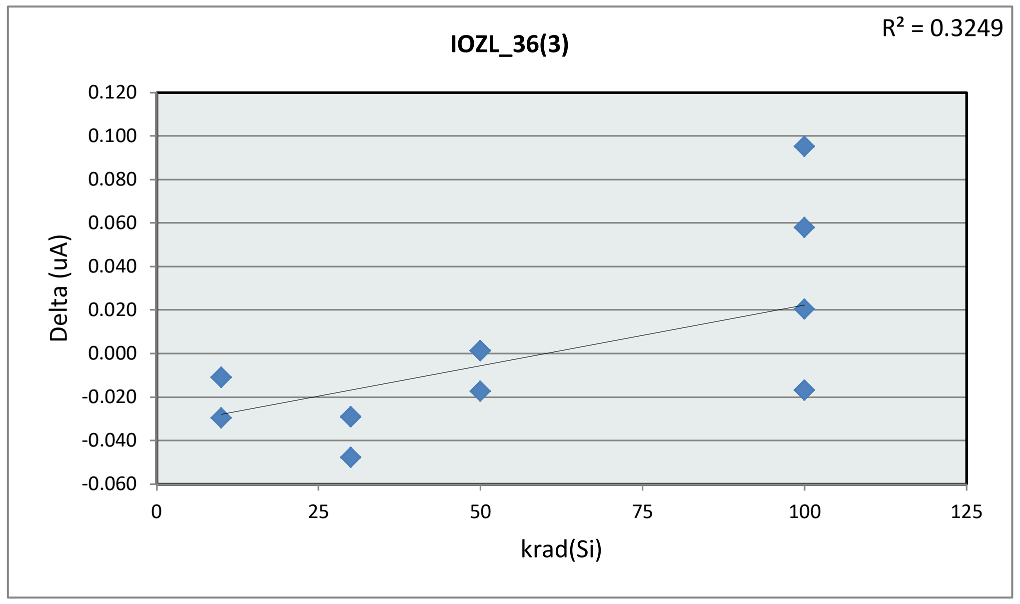


	IOZL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.001	-0.168	-0.007	-0.121
Average	0.001	-0.149	0.000	-0.076
Max	0.001	-0.093	0.012	-0.046
UL	350.000	350.000	350.000	350.000

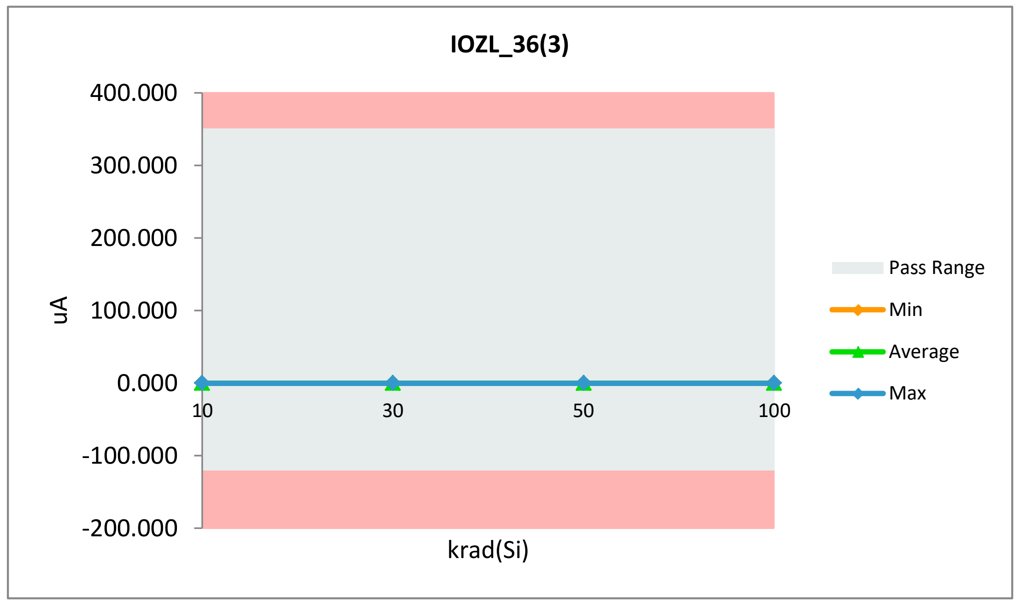


LDR Biased TID Report
SN55LVCP22A-SP

		IOZL_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		350	350	
Min Limit		-120	-120	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.016	-0.005	-0.011
10	5	-0.016	-0.005	-0.011
10	7	-0.035	-0.005	-0.030
10	11	-0.035	-0.005	-0.030
10	15	-0.016	-0.005	-0.011
10	20	-0.016	-0.005	-0.011
10	21	-0.016	-0.005	-0.011
10	24	-0.016	-0.005	-0.011
30	1	-0.016	0.013	-0.029
30	5	-0.016	0.013	-0.029
30	7	-0.035	0.013	-0.048
30	11	-0.035	0.013	-0.048
30	15	-0.016	0.013	-0.029
30	20	-0.016	0.013	-0.029
30	21	-0.016	0.013	-0.029
30	24	-0.016	0.013	-0.029
50	1	-0.016	-0.017	0.001
50	5	-0.016	-0.017	0.001
50	7	-0.035	-0.017	-0.017
50	11	-0.035	-0.017	-0.017
50	15	-0.016	-0.017	0.001
50	20	-0.016	-0.017	0.001
50	21	-0.016	-0.017	0.001
50	24	-0.016	-0.017	0.001
100	3	-0.016	-0.074	0.058
100	8	0.003	-0.092	0.095
100	12	-0.016	0.001	-0.017
100	13	-0.016	0.001	-0.017
100	16	-0.016	-0.111	0.095
100	17	-0.016	0.001	-0.017
100	18	-0.016	-0.036	0.020
100	19	-0.016	0.001	-0.017
	Max	0.003	0.013	0.095
	Average	-0.019	-0.012	-0.007
	Min	-0.035	-0.111	-0.048
	Std Dev	0.008	0.030	0.033



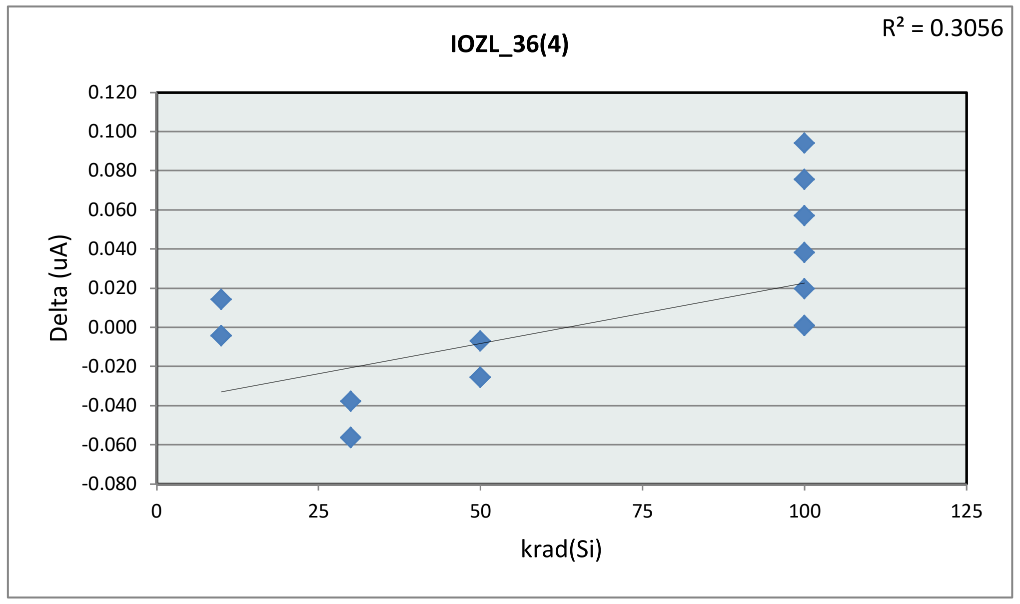
	IOZL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.005	0.013	-0.017	-0.111
Average	-0.005	0.013	-0.017	-0.039
Max	-0.005	0.013	-0.017	0.001
UL	350.000	350.000	350.000	350.000



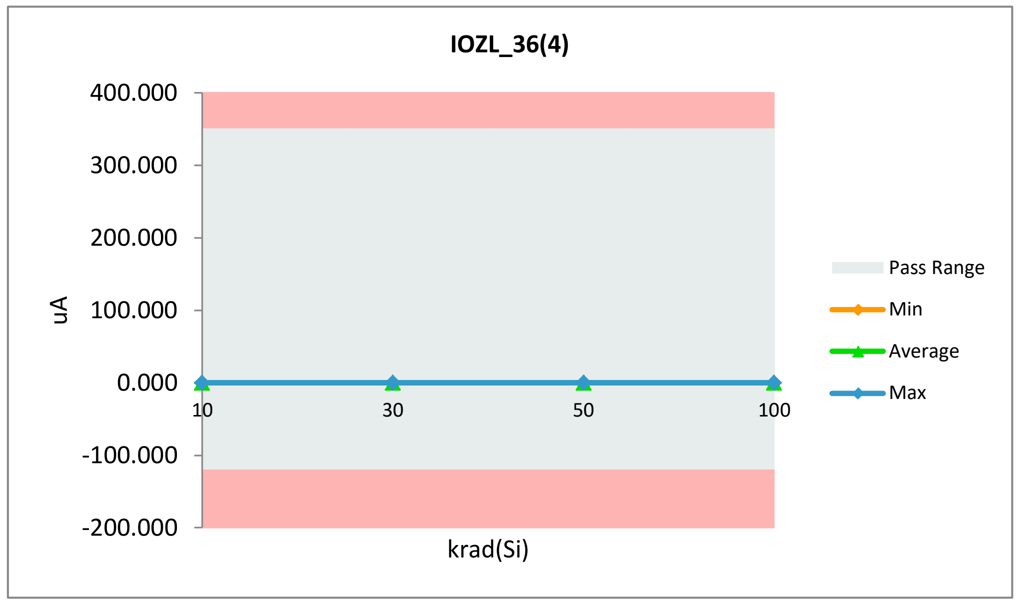
LDR Biased TID Report
SN55LVCP22A-SP

	IOZL_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.019	-0.015	-0.004
10	5	-0.019	-0.015	-0.004
10	7	-0.001	-0.015	0.014
10	11	-0.019	-0.015	-0.004
10	15	-0.019	-0.015	-0.004
10	20	-0.019	-0.033	0.014
10	21	-0.019	-0.015	-0.004
10	24	-0.019	-0.015	-0.004
30	1	-0.019	0.037	-0.056
30	5	-0.019	0.037	-0.056
30	7	-0.001	0.037	-0.038
30	11	-0.019	0.037	-0.056
30	15	-0.019	0.037	-0.056
30	20	-0.019	0.037	-0.056
30	21	-0.019	0.037	-0.056
30	24	-0.019	0.037	-0.056
50	1	-0.019	0.006	-0.026
50	5	-0.019	0.006	-0.026
50	7	-0.001	0.006	-0.007
50	11	-0.019	0.006	-0.026
50	15	-0.019	0.006	-0.026
50	20	-0.019	0.006	-0.026
50	21	-0.019	-0.012	-0.007
50	24	-0.019	0.006	-0.026
100	3	-0.019	-0.076	0.057
100	8	-0.019	-0.095	0.075
100	12	-0.019	-0.020	0.001
100	13	-0.019	-0.020	0.001
100	16	-0.019	-0.113	0.094
100	17	-0.019	-0.020	0.001
100	18	-0.019	-0.057	0.038
100	19	-0.001	-0.020	0.020
	Max	-0.001	0.037	0.094
	Average	-0.017	-0.007	-0.010
	Min	-0.019	-0.113	-0.056
	Std Dev	0.006	0.038	0.038



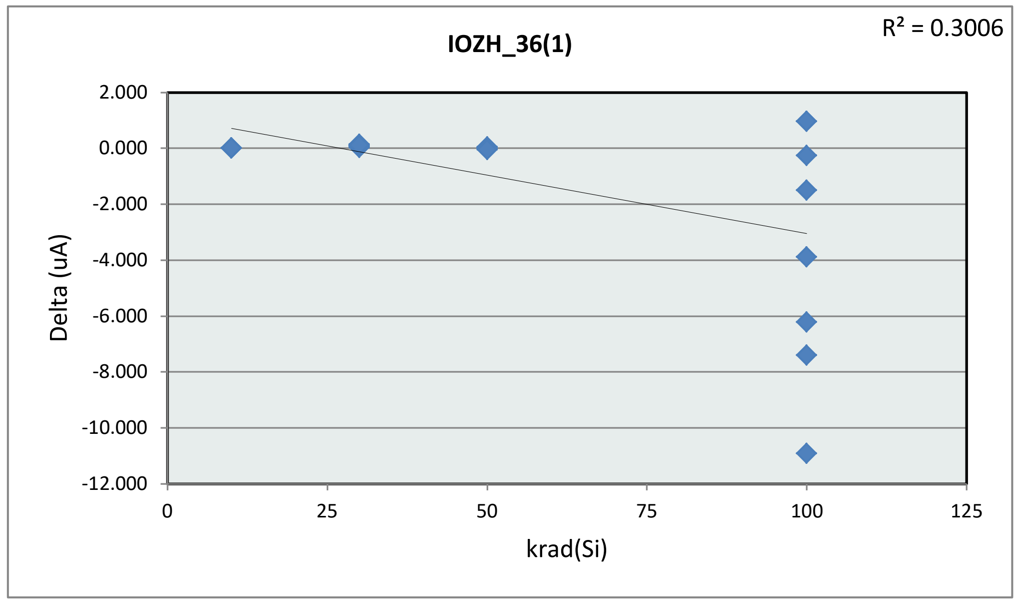
	IOZL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.033	0.037	-0.012	-0.113
Average	-0.017	0.037	0.004	-0.053
Max	-0.015	0.037	0.006	-0.020
UL	350.000	350.000	350.000	350.000



LDR Biased TID Report
SN55LVCP22A-SP

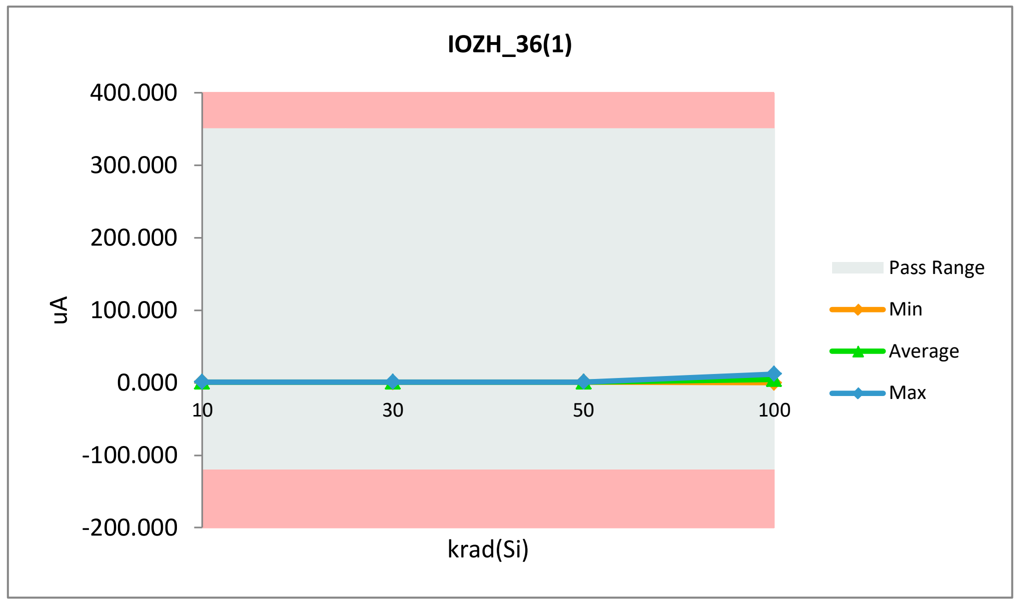
	IOZH_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.989	0.985	0.004
10	5	1.008	1.004	0.004
10	7	0.971	0.966	0.004
10	11	1.008	1.004	0.004
10	15	1.045	1.041	0.004
10	20	0.952	0.948	0.004
10	21	0.971	0.966	0.004
10	24	1.008	1.004	0.004
30	1	0.989	0.911	0.078
30	5	1.008	0.986	0.022
30	7	0.971	0.911	0.059
30	11	1.008	0.911	0.096
30	15	1.045	0.911	0.133
30	20	0.952	0.837	0.115
30	21	0.971	0.911	0.059
30	24	1.008	0.911	0.096
50	1	0.989	1.010	-0.021
50	5	1.008	1.010	-0.002
50	7	0.971	0.973	-0.002
50	11	1.008	0.973	0.035
50	15	1.045	1.028	0.017
50	20	0.952	0.935	0.017
50	21	0.971	0.973	-0.002
50	24	1.008	1.066	-0.058
100	3	1.008	7.221	-6.213
100	8	1.008	8.413	-7.405
100	12	1.026	0.071	0.956
100	13	1.008	1.262	-0.254
100	16	1.064	11.988	-10.924
100	17	0.952	2.454	-1.502
100	18	0.952	4.838	-3.886
100	19	1.026	0.071	0.956
	Max	1.064	11.988	0.956
	Average	0.997	1.859	-0.862
	Min	0.952	0.071	-10.924
	Std Dev	0.031	2.600	2.592



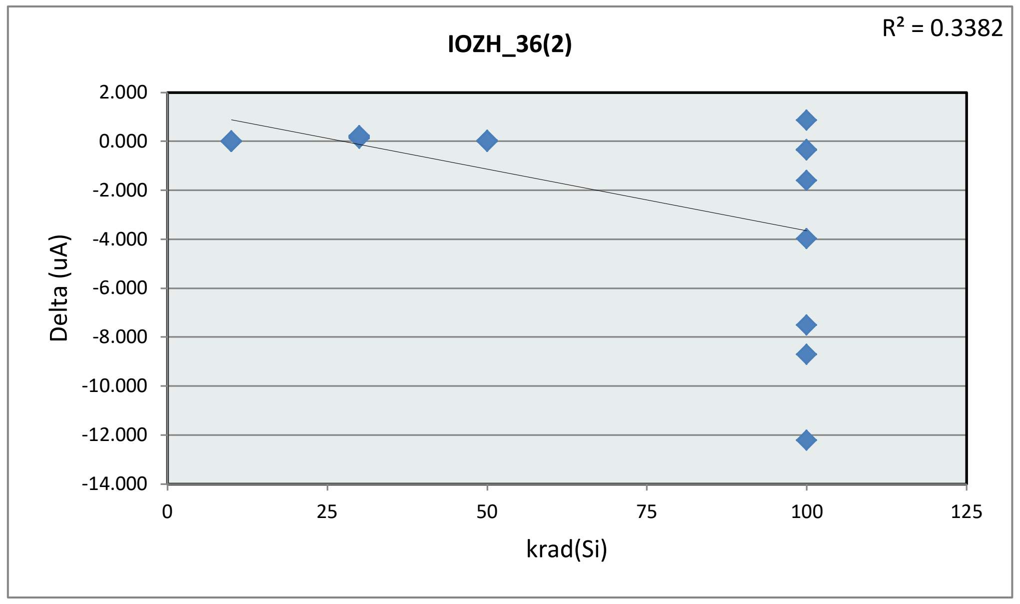
	IOZH_36(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	350	uA
Min Limit	-120	uA

krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.948	0.837	0.935	0.071
Average	0.990	0.911	0.996	4.540
Max	1.041	0.986	1.066	11.988
UL	350.000	350.000	350.000	350.000

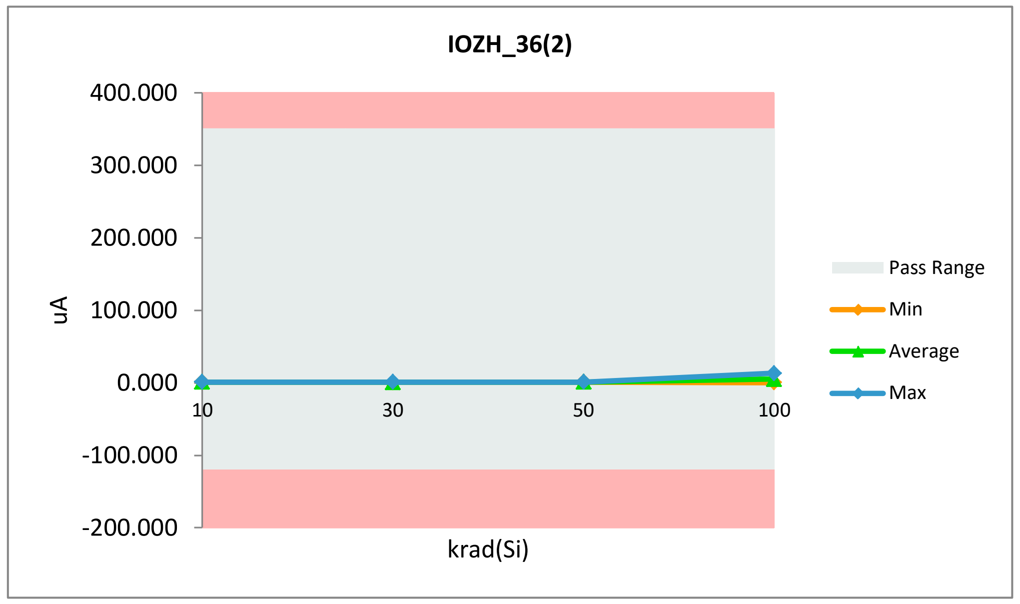


LDR Biased TID Report
SN55LVCP22A-SP

		IOZH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.981	0.988	-0.007
10	5	1.000	1.007	-0.007
10	7	0.962	0.969	-0.007
10	11	1.000	0.988	0.012
10	15	1.037	1.044	-0.007
10	20	0.962	0.951	0.012
10	21	0.962	0.969	-0.007
10	24	1.018	1.007	0.012
30	1	0.981	0.801	0.180
30	5	1.000	0.875	0.124
30	7	0.962	0.801	0.162
30	11	1.000	0.801	0.199
30	15	1.037	0.875	0.161
30	20	0.962	0.801	0.162
30	21	0.962	0.801	0.162
30	24	1.018	0.801	0.217
50	1	0.981	0.998	-0.017
50	5	1.000	0.998	0.002
50	7	0.962	0.961	0.002
50	11	1.000	0.961	0.039
50	15	1.037	1.016	0.020
50	20	0.962	0.923	0.039
50	21	0.962	0.961	0.002
50	24	1.018	1.016	0.002
100	3	1.000	8.518	-7.518
100	8	1.000	9.709	-8.709
100	12	1.037	1.373	-0.336
100	13	1.000	1.373	-0.373
100	16	1.074	13.282	-12.208
100	17	0.962	2.564	-1.602
100	18	0.962	4.946	-3.984
100	19	1.037	0.182	0.854
	Max	1.074	13.282	0.854
	Average	0.995	2.008	-1.013
	Min	0.962	0.182	-12.208
	Std Dev	0.031	2.951	2.942



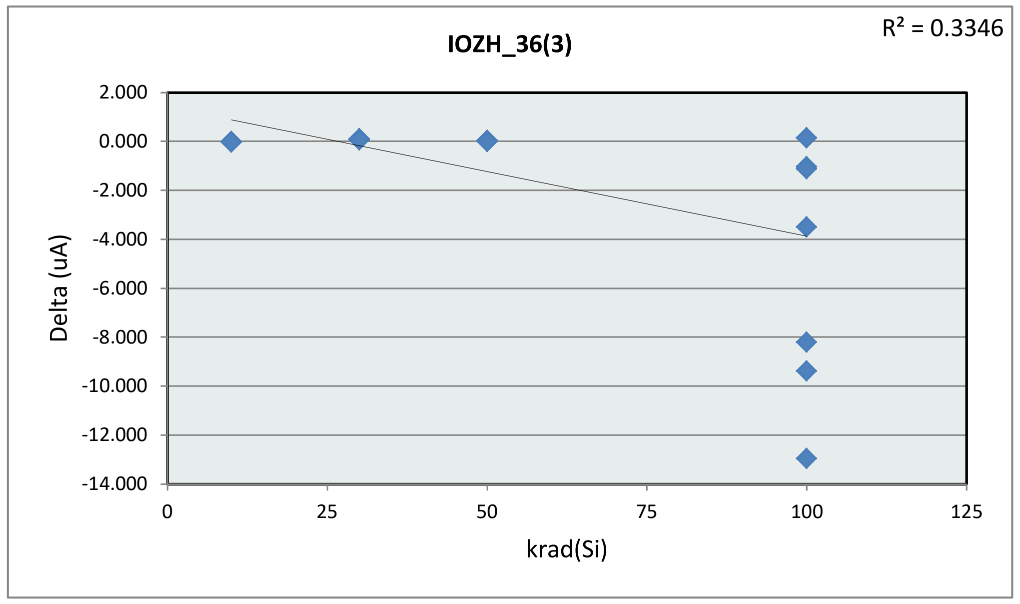
	IOZH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.951	0.801	0.923	0.182
Average	0.990	0.820	0.979	5.243
Max	1.044	0.875	1.016	13.282
UL	350.000	350.000	350.000	350.000



LDR Biased TID Report
SN55LVCP22A-SP

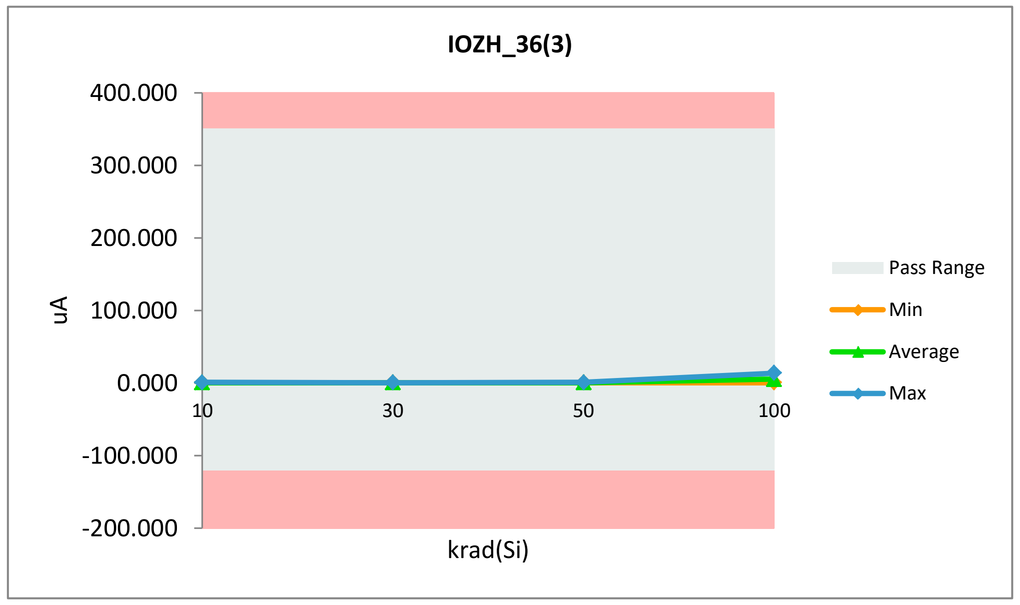
	IOZH_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.935	0.964	-0.029
10	5	0.954	0.983	-0.029
10	7	0.917	0.927	-0.010
10	11	0.935	0.945	-0.010
10	15	1.010	1.020	-0.010
10	20	0.917	0.927	-0.010
10	21	0.935	0.945	-0.010
10	24	0.973	1.001	-0.029
30	1	0.935	0.833	0.102
30	5	0.954	0.908	0.046
30	7	0.917	0.833	0.083
30	11	0.935	0.833	0.102
30	15	1.010	0.908	0.102
30	20	0.917	0.833	0.083
30	21	0.935	0.833	0.102
30	24	0.973	0.908	0.065
50	1	0.935	0.934	0.001
50	5	0.954	0.953	0.001
50	7	0.917	0.897	0.020
50	11	0.935	0.916	0.020
50	15	1.010	0.990	0.020
50	20	0.917	0.897	0.020
50	21	0.935	0.916	0.020
50	24	0.973	0.990	-0.018
100	3	0.973	9.190	-8.217
100	8	0.991	10.383	-9.392
100	12	0.991	0.846	0.146
100	13	0.991	2.038	-1.047
100	16	0.991	13.959	-12.968
100	17	0.917	2.038	-1.121
100	18	0.917	4.422	-3.505
100	19	0.991	0.846	0.146
	Max	1.010	13.959	0.146
	Average	0.953	2.057	-1.104
	Min	0.917	0.833	-12.968
	Std Dev	0.032	3.118	3.109



	IOZH_36(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	350	uA
Min Limit	-120	uA

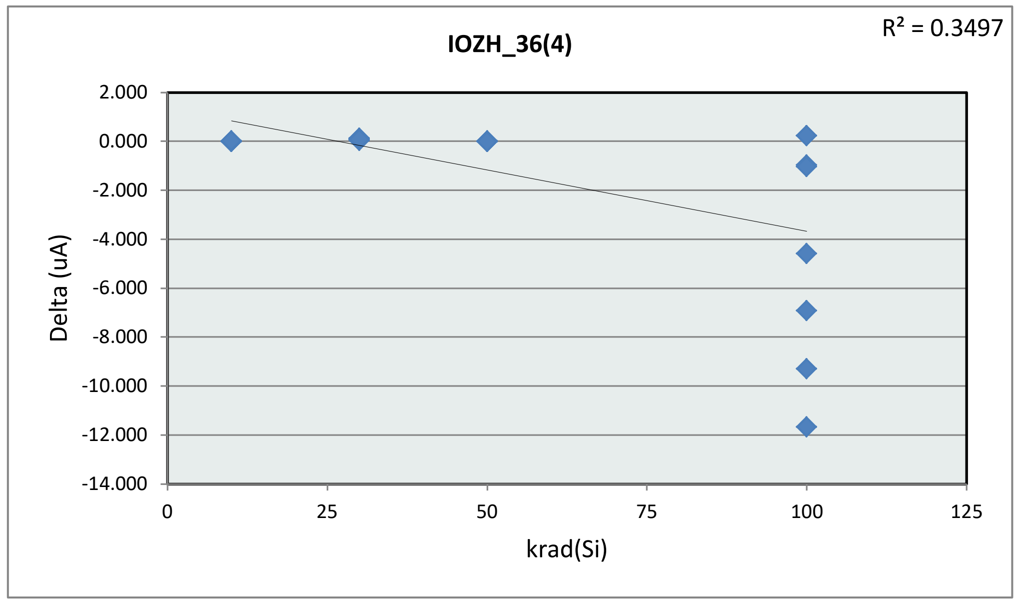
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.927	0.833	0.897	0.846
Average	0.964	0.861	0.937	5.465
Max	1.020	0.908	0.990	13.959
UL	350.000	350.000	350.000	350.000



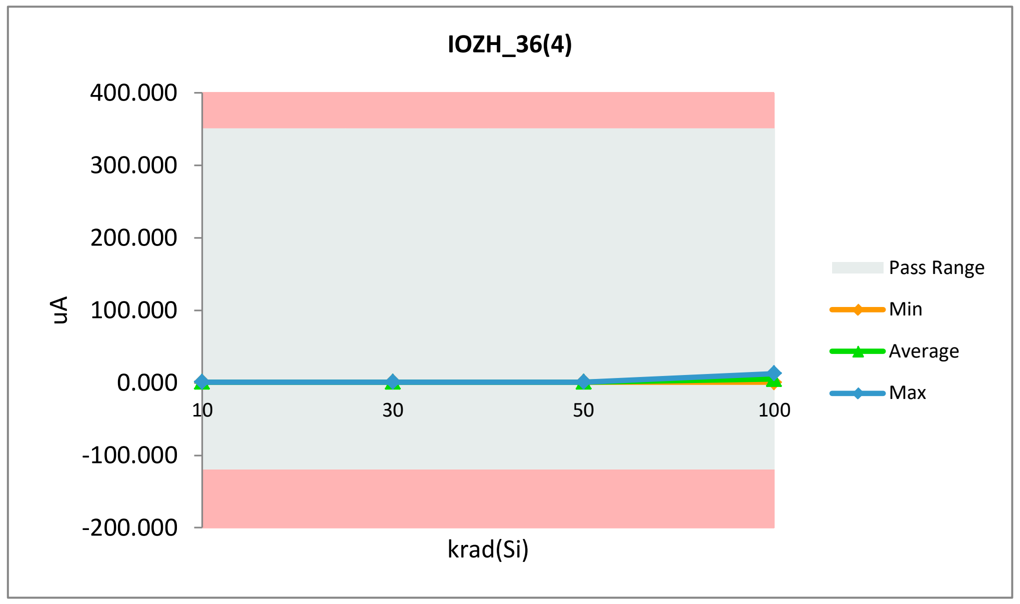
LDR Biased TID Report
SN55LVCP22A-SP

	IOZH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.967	0.971	-0.004
10	5	0.985	0.990	-0.004
10	7	0.930	0.934	-0.004
10	11	0.967	0.953	0.014
10	15	1.041	1.027	0.014
10	20	0.948	0.934	0.014
10	21	0.948	0.953	-0.004
10	24	1.004	0.990	0.014
30	1	0.967	0.856	0.111
30	5	0.985	0.930	0.055
30	7	0.930	0.856	0.074
30	11	0.967	0.856	0.111
30	15	1.041	0.930	0.111
30	20	0.948	0.930	0.018
30	21	0.948	0.856	0.092
30	24	1.004	0.930	0.074
50	1	0.967	0.973	-0.006
50	5	0.985	0.992	-0.006
50	7	0.930	0.936	-0.006
50	11	0.967	0.955	0.012
50	15	1.041	1.029	0.012
50	20	0.948	0.936	0.012
50	21	0.948	0.955	-0.006
50	24	1.004	1.010	-0.006
100	3	1.004	7.930	-6.926
100	8	1.004	10.311	-9.307
100	12	1.004	0.787	0.217
100	13	1.004	1.978	-0.974
100	16	1.023	12.692	-11.669
100	17	0.948	1.978	-1.030
100	18	0.948	5.549	-4.601
100	19	1.004	0.787	0.217
	Max	1.041	12.692	0.217
	Average	0.979	2.022	-1.043
	Min	0.930	0.787	-11.669
	Std Dev	0.033	2.901	2.892

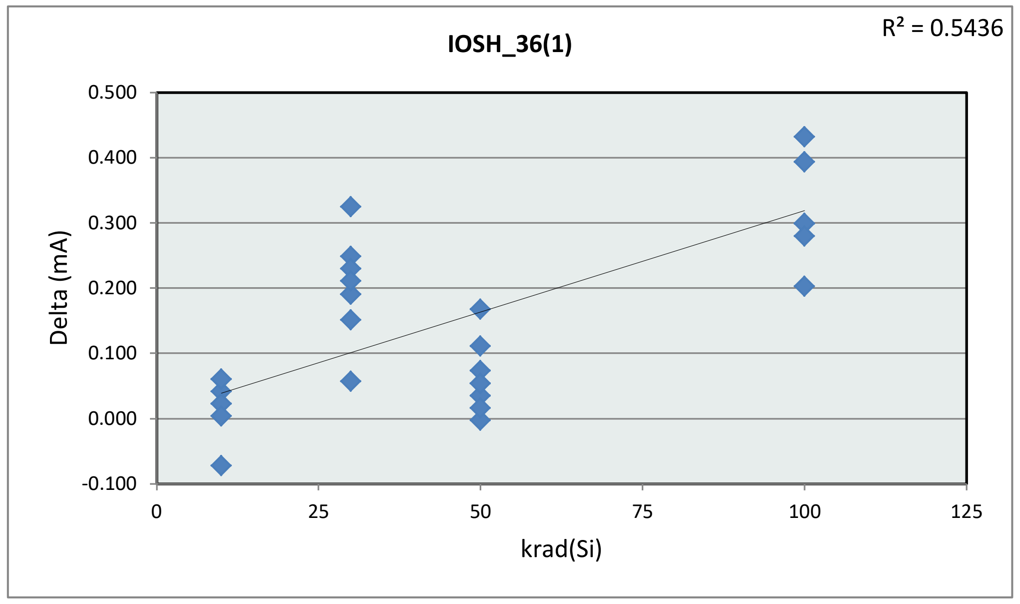


	IOZH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.934	0.856	0.936	0.787
Average	0.969	0.893	0.973	5.252
Max	1.027	0.930	1.029	12.692
UL	350.000	350.000	350.000	350.000

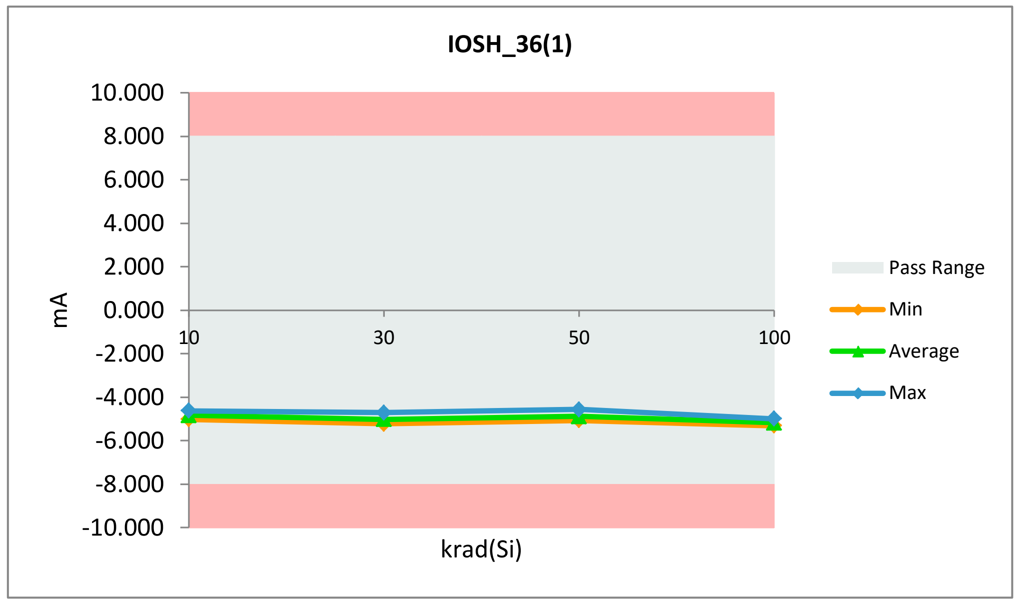


LDR Biased TID Report
SN55LVCP22A-SP

		IOSH_36(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.770	-4.811	0.041
10	5	-4.732	-4.735	0.004
10	7	-4.561	-4.622	0.060
10	11	-4.808	-4.830	0.022
10	15	-4.864	-4.925	0.060
10	20	-4.997	-5.020	0.022
10	21	-4.770	-4.697	-0.072
10	24	-5.016	-5.020	0.004
30	1	-4.770	-4.960	0.190
30	5	-4.732	-4.922	0.190
30	7	-4.561	-4.712	0.151
30	11	-4.808	-5.132	0.324
30	15	-4.864	-5.113	0.249
30	20	-4.997	-5.227	0.230
30	21	-4.770	-4.827	0.057
30	24	-5.016	-5.227	0.211
50	1	-4.770	-4.881	0.111
50	5	-4.732	-4.767	0.035
50	7	-4.561	-4.558	-0.003
50	11	-4.808	-4.975	0.168
50	15	-4.864	-4.937	0.073
50	20	-4.997	-5.051	0.054
50	21	-4.770	-4.786	0.016
50	24	-5.016	-5.070	0.054
100	3	-4.827	-5.125	0.298
100	8	-4.864	-5.258	0.394
100	12	-4.808	-5.239	0.431
100	13	-4.921	-5.220	0.299
100	16	-4.883	-5.315	0.432
100	17	-4.789	-4.991	0.202
100	18	-4.751	-5.030	0.279
100	19	-4.845	-5.239	0.394
	Max	-4.561	-4.558	0.432
	Average	-4.820	-4.976	0.156
	Min	-5.016	-5.315	-0.072
	Std Dev	0.124	0.203	0.143

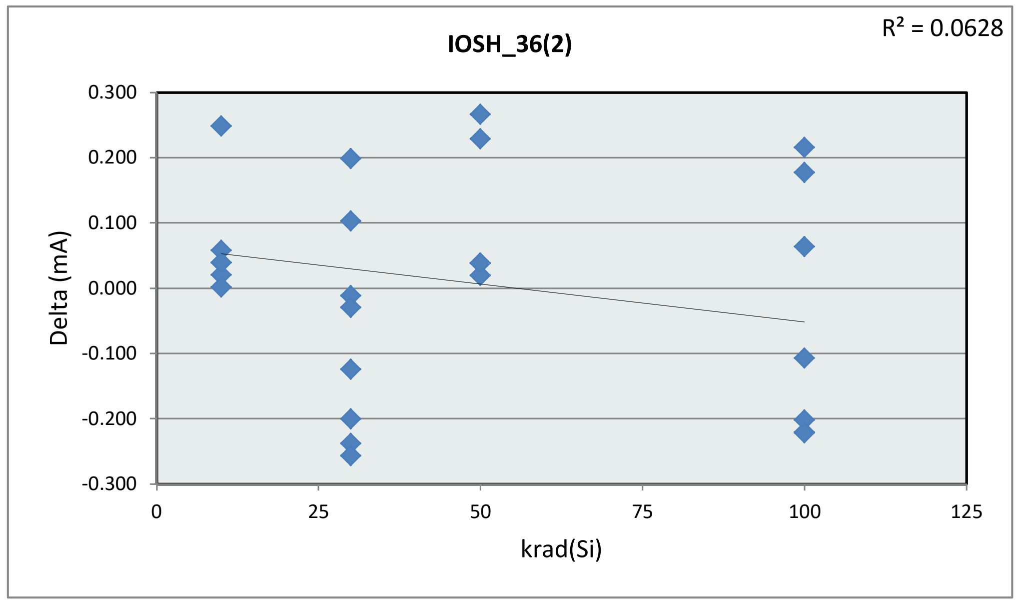


	IOSH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.020	-5.227	-5.070	-5.315
Average	-4.832	-5.015	-4.878	-5.177
Max	-4.622	-4.712	-4.558	-4.991
UL	8.000	8.000	8.000	8.000

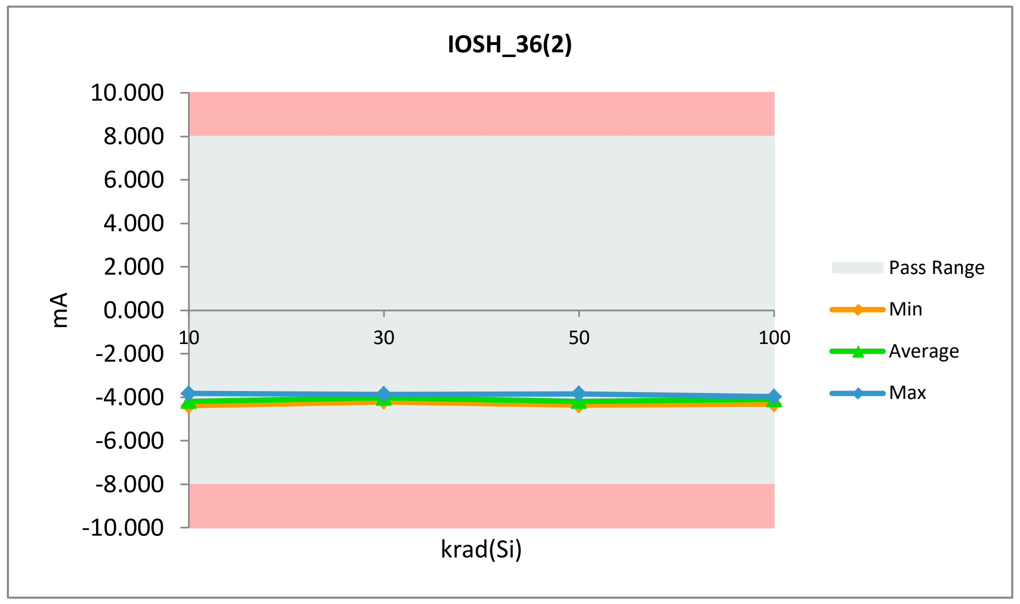


LDR Biased TID Report
SN55LVCP22A-SP

		IOSH_36(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.237	-4.257	0.020
10	5	-3.820	-3.821	0.001
10	7	-3.877	-4.125	0.248
10	11	-4.275	-4.333	0.058
10	15	-4.047	-4.295	0.248
10	20	-4.351	-4.390	0.039
10	21	-4.161	-4.200	0.039
10	24	-4.010	-4.049	0.039
30	1	-4.237	-4.037	-0.200
30	5	-3.820	-3.922	0.102
30	7	-3.877	-3.865	-0.012
30	11	-4.275	-4.037	-0.238
30	15	-4.047	-4.018	-0.029
30	20	-4.351	-4.094	-0.257
30	21	-4.161	-4.037	-0.124
30	24	-4.010	-4.208	0.198
50	1	-4.237	-4.276	0.039
50	5	-3.820	-3.839	0.019
50	7	-3.877	-4.105	0.228
50	11	-4.275	-4.314	0.039
50	15	-4.047	-4.314	0.266
50	20	-4.351	-4.371	0.020
50	21	-4.161	-4.200	0.039
50	24	-4.010	-4.048	0.038
100	3	-4.218	-3.997	-0.221
100	8	-4.351	-4.244	-0.107
100	12	-3.877	-4.054	0.177
100	13	-4.256	-4.320	0.064
100	16	-4.294	-4.073	-0.221
100	17	-4.180	-3.978	-0.202
100	18	-4.199	-3.978	-0.221
100	19	-3.896	-4.111	0.215
	Max	-3.820	-3.821	0.266
	Average	-4.113	-4.122	0.009
	Min	-4.351	-4.390	-0.257
	Std Dev	0.181	0.159	0.158



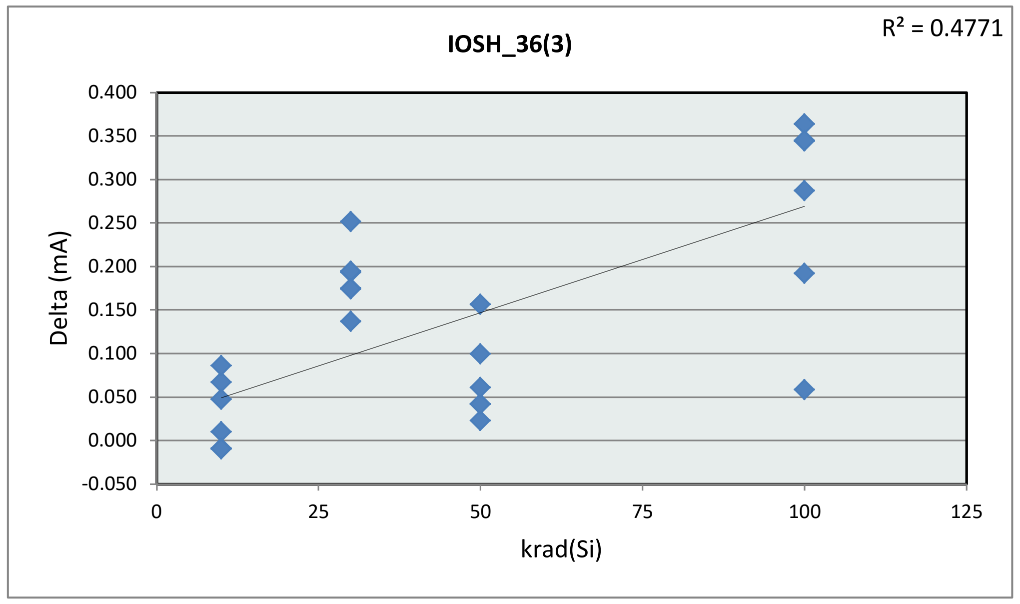
	IOSH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.390	-4.208	-4.371	-4.320
Average	-4.184	-4.027	-4.183	-4.094
Max	-3.821	-3.865	-3.839	-3.978
UL	8.000	8.000	8.000	8.000



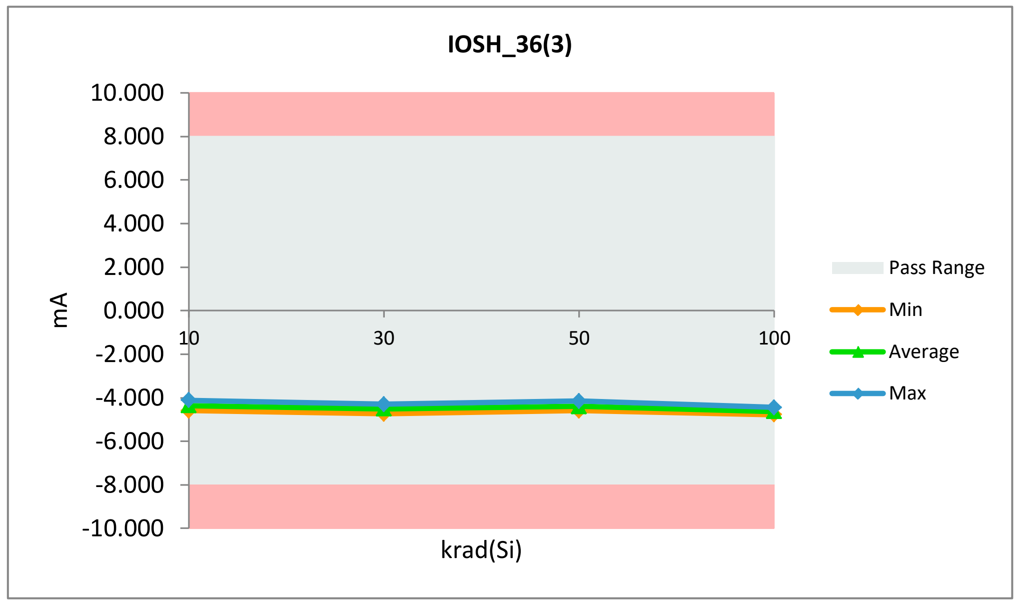
LDR Biased TID Report
SN55LVCP22A-SP

	IOSH_36(3)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	mA	mA	
Max Limit	8	8	
Min Limit	-8	-8	

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.316	-4.383	0.067
10	5	-4.164	-4.174	0.010
10	7	-4.126	-4.117	-0.009
10	11	-4.431	-4.421	-0.010
10	15	-4.354	-4.345	-0.009
10	20	-4.545	-4.592	0.047
10	21	-4.202	-4.288	0.086
10	24	-4.488	-4.535	0.048
30	1	-4.316	-4.453	0.137
30	5	-4.164	-4.357	0.193
30	7	-4.126	-4.300	0.174
30	11	-4.431	-4.605	0.174
30	15	-4.354	-4.529	0.175
30	20	-4.545	-4.739	0.194
30	21	-4.202	-4.376	0.174
30	24	-4.488	-4.739	0.251
50	1	-4.316	-4.415	0.099
50	5	-4.164	-4.206	0.042
50	7	-4.126	-4.149	0.023
50	11	-4.431	-4.587	0.156
50	15	-4.354	-4.396	0.042
50	20	-4.545	-4.587	0.042
50	21	-4.202	-4.244	0.042
50	24	-4.488	-4.549	0.061
100	3	-4.240	-4.584	0.344
100	8	-4.373	-4.718	0.345
100	12	-4.259	-4.623	0.364
100	13	-4.583	-4.775	0.192
100	16	-4.316	-4.680	0.364
100	17	-4.164	-4.451	0.287
100	18	-4.469	-4.527	0.058
100	19	-4.297	-4.642	0.345
	Max	-4.126	-4.117	0.364
	Average	-4.331	-4.471	0.141
	Min	-4.583	-4.775	-0.010
	Std Dev	0.143	0.183	0.120



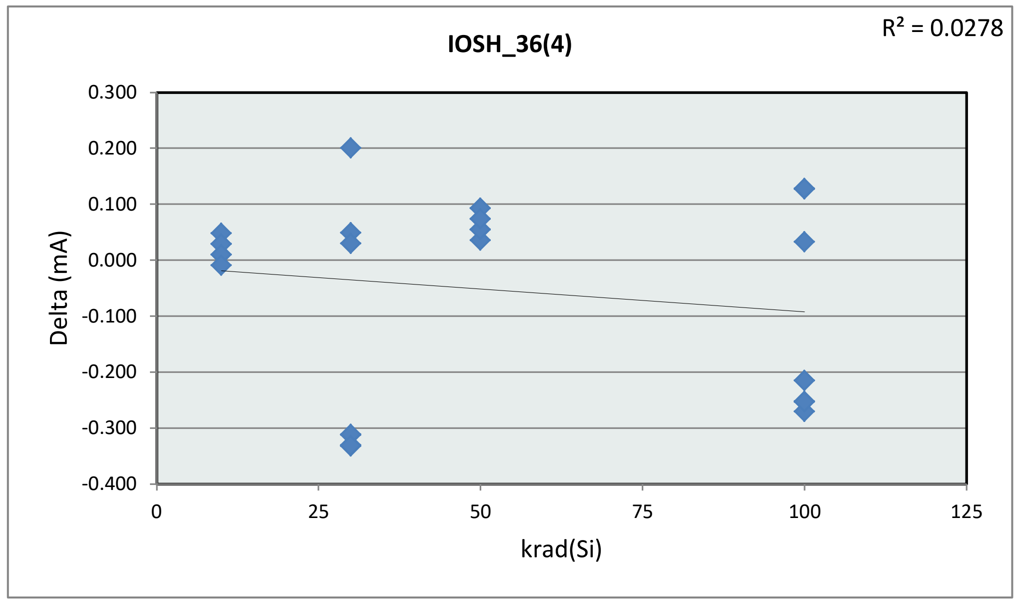
	IOSH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.592	-4.739	-4.587	-4.775
Average	-4.357	-4.512	-4.392	-4.625
Max	-4.117	-4.300	-4.149	-4.451
UL	8.000	8.000	8.000	8.000



LDR Biased TID Report
SN55LVCP22A-SP

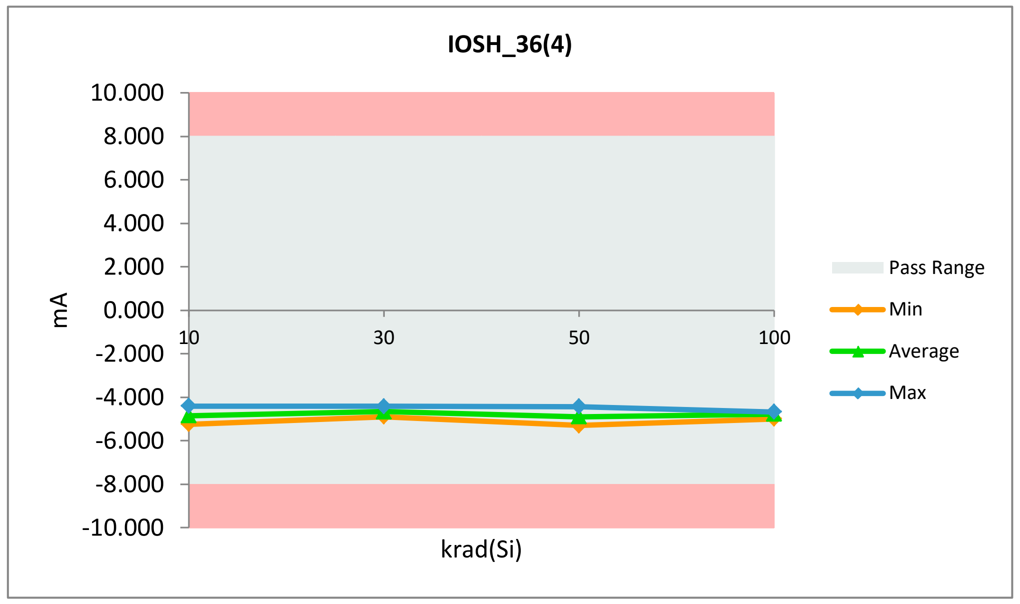
	IOSH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.923	-4.933	0.010
10	5	-4.372	-4.401	0.029
10	7	-4.752	-4.781	0.029
10	11	-5.075	-5.085	0.010
10	15	-4.600	-4.648	0.048
10	20	-5.208	-5.237	0.029
10	21	-4.866	-4.876	0.010
10	24	-4.828	-4.819	-0.009
30	1	-4.923	-4.611	-0.312
30	5	-4.372	-4.573	0.201
30	7	-4.752	-4.420	-0.332
30	11	-5.075	-4.744	-0.331
30	15	-4.600	-4.649	0.049
30	20	-5.208	-4.896	-0.312
30	21	-4.866	-4.535	-0.331
30	24	-4.828	-4.858	0.030
50	1	-4.923	-4.997	0.074
50	5	-4.372	-4.427	0.055
50	7	-4.752	-4.807	0.055
50	11	-5.075	-5.111	0.036
50	15	-4.600	-4.693	0.093
50	20	-5.208	-5.301	0.093
50	21	-4.866	-4.921	0.055
50	24	-4.828	-4.902	0.074
100	3	-4.543	-4.670	0.127
100	8	-4.676	-4.804	0.128
100	12	-4.885	-4.670	-0.215
100	13	-5.189	-4.918	-0.271
100	16	-4.961	-4.994	0.033
100	17	-4.885	-4.670	-0.215
100	18	-5.018	-4.766	-0.252
100	19	-4.923	-4.670	-0.253
	Max	-4.372	-4.401	0.201
	Average	-4.842	-4.793	-0.049
	Min	-5.208	-5.301	-0.332
	Std Dev	0.237	0.220	0.167



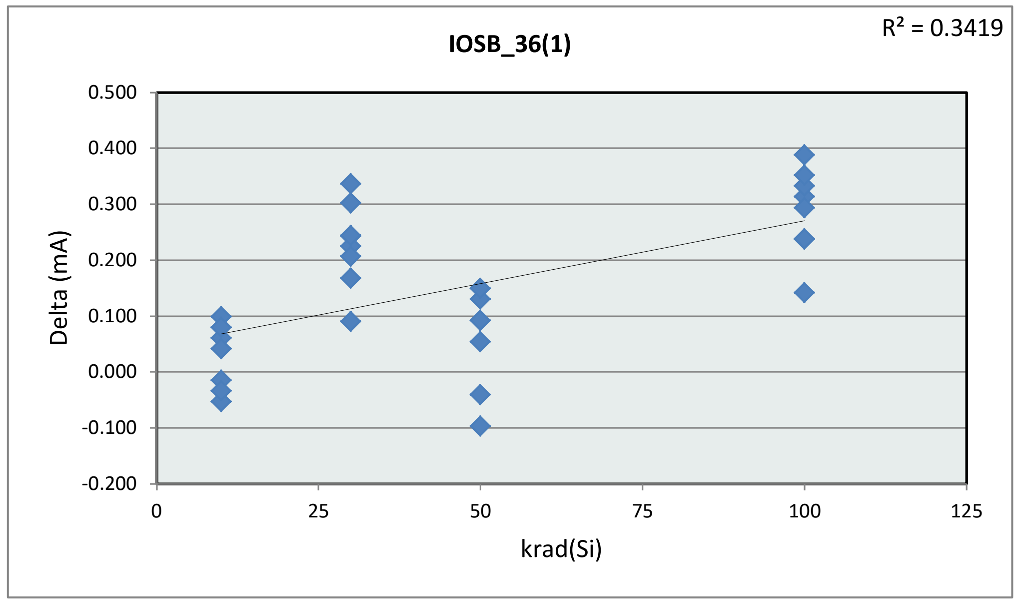
	IOSH_36(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.237	-4.896	-5.301	-4.994
Average	-4.847	-4.661	-4.895	-4.770
Max	-4.401	-4.420	-4.427	-4.670
UL	8.000	8.000	8.000	8.000

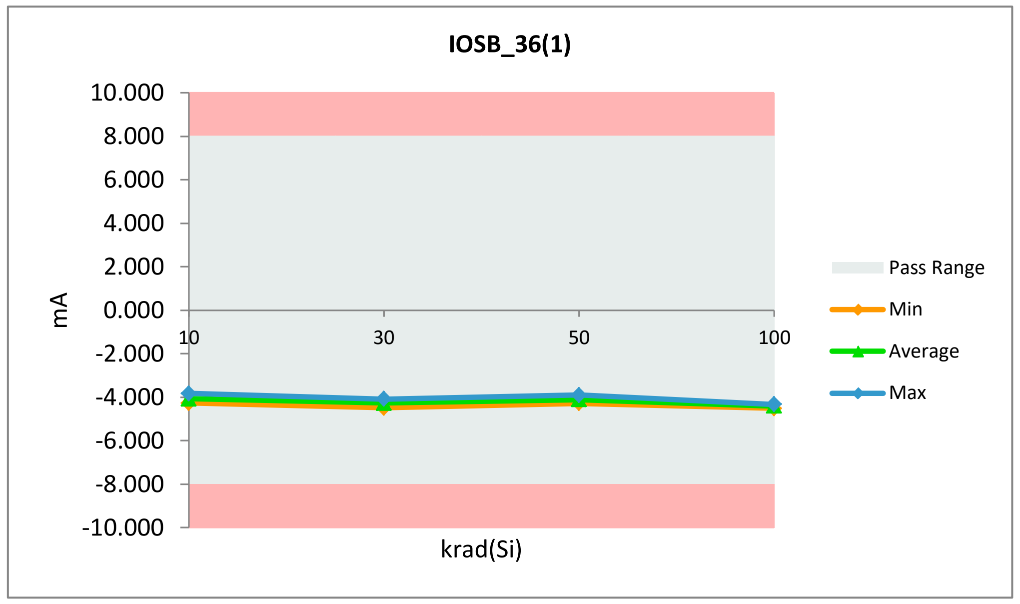


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.107	-4.053	-0.053
10	5	-3.955	-4.053	0.098
10	7	-3.747	-3.826	0.079
10	11	-4.088	-4.148	0.060
10	15	-4.069	-4.110	0.041
10	20	-4.220	-4.205	-0.015
10	21	-3.993	-3.959	-0.034
10	24	-4.182	-4.262	0.079
30	1	-4.107	-4.274	0.167
30	5	-3.955	-4.198	0.243
30	7	-3.747	-4.083	0.336
30	11	-4.088	-4.312	0.224
30	15	-4.069	-4.312	0.243
30	20	-4.220	-4.427	0.207
30	21	-3.993	-4.083	0.090
30	24	-4.182	-4.484	0.302
50	1	-4.107	-4.009	-0.098
50	5	-3.955	-4.047	0.092
50	7	-3.747	-3.895	0.149
50	11	-4.088	-4.217	0.130
50	15	-4.069	-4.217	0.149
50	20	-4.220	-4.274	0.054
50	21	-3.993	-3.952	-0.041
50	24	-4.182	-4.274	0.092
100	3	-4.145	-4.382	0.237
100	8	-4.182	-4.420	0.238
100	12	-4.107	-4.420	0.313
100	13	-4.220	-4.362	0.142
100	16	-4.182	-4.515	0.333
100	17	-3.936	-4.324	0.388
100	18	-4.050	-4.343	0.293
100	19	-4.088	-4.439	0.351
	Max	-3.747	-3.826	0.388
	Average	-4.062	-4.215	0.153
	Min	-4.220	-4.515	-0.098
	Std Dev	0.134	0.181	0.131

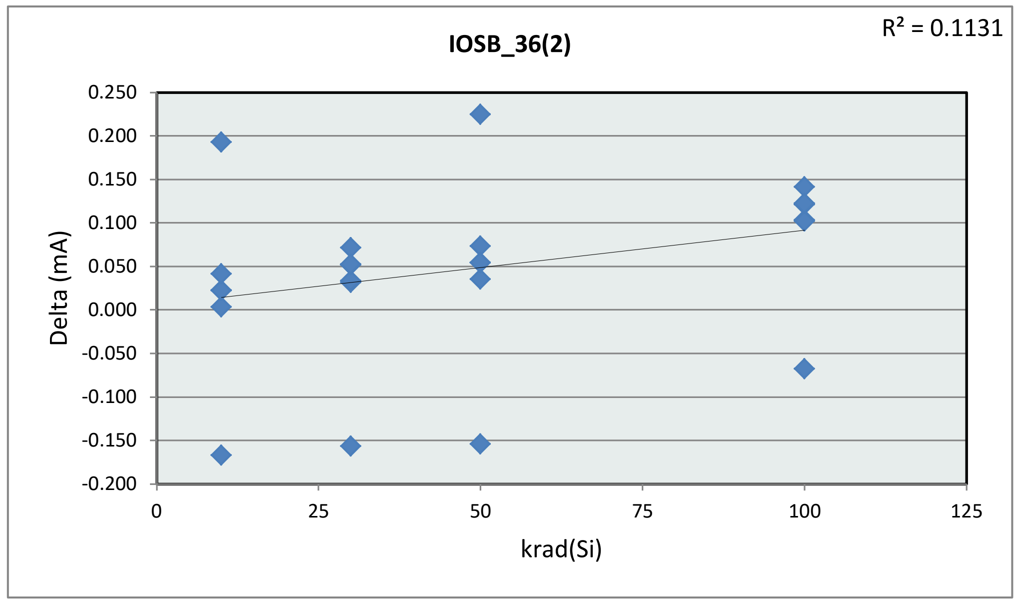


	IOSB_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.262	-4.484	-4.274	-4.515
Average	-4.077	-4.272	-4.111	-4.401
Max	-3.826	-4.083	-3.895	-4.324
UL	8.000	8.000	8.000	8.000

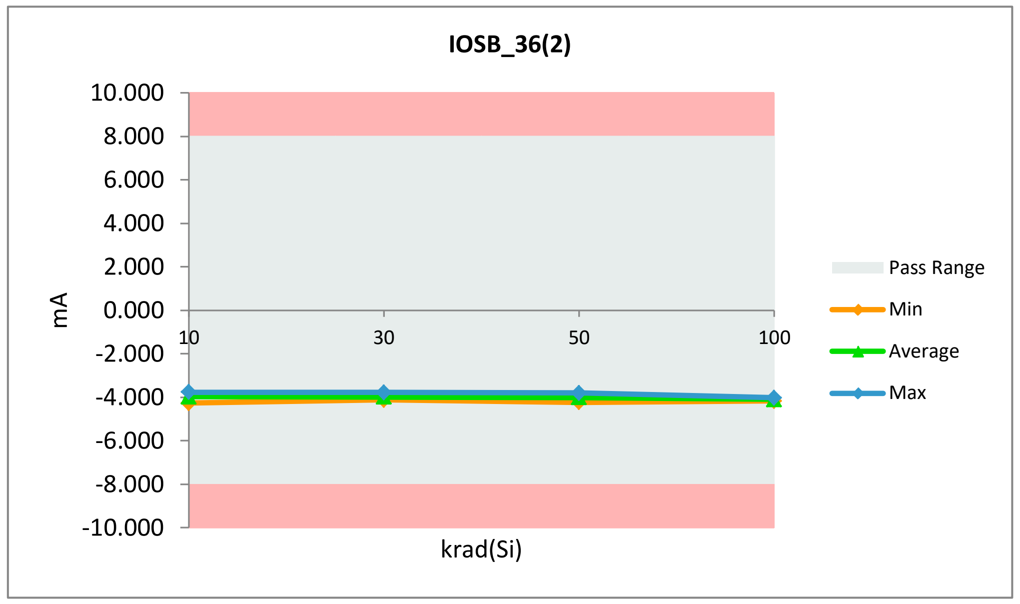


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-3.917	-3.940	0.022
10	5	-4.050	-3.883	-0.167
10	7	-3.747	-3.769	0.022
10	11	-3.974	-3.996	0.022
10	15	-4.012	-4.015	0.003
10	20	-4.050	-4.072	0.022
10	21	-3.841	-3.883	0.041
10	24	-4.069	-4.262	0.193
30	1	-3.917	-3.969	0.052
30	5	-4.050	-3.893	-0.157
30	7	-3.747	-3.778	0.031
30	11	-3.974	-4.026	0.052
30	15	-4.012	-4.045	0.033
30	20	-4.050	-4.121	0.071
30	21	-3.841	-3.893	0.052
30	24	-4.069	-4.121	0.052
50	1	-3.917	-3.952	0.035
50	5	-4.050	-3.895	-0.154
50	7	-3.747	-3.801	0.054
50	11	-3.974	-4.028	0.054
50	15	-4.012	-4.236	0.225
50	20	-4.050	-4.104	0.054
50	21	-3.841	-3.914	0.073
50	24	-4.069	-4.123	0.054
100	3	-3.917	-4.038	0.121
100	8	-3.993	-4.115	0.122
100	12	-4.163	-4.096	-0.067
100	13	-4.069	-4.172	0.103
100	16	-4.031	-4.172	0.141
100	17	-3.917	-4.019	0.102
100	18	-3.936	-4.038	0.102
100	19	-3.974	-4.096	0.122
	Max	-3.747	-3.769	0.225
	Average	-3.968	-4.015	0.046
	Min	-4.163	-4.262	-0.167
	Std Dev	0.104	0.126	0.087

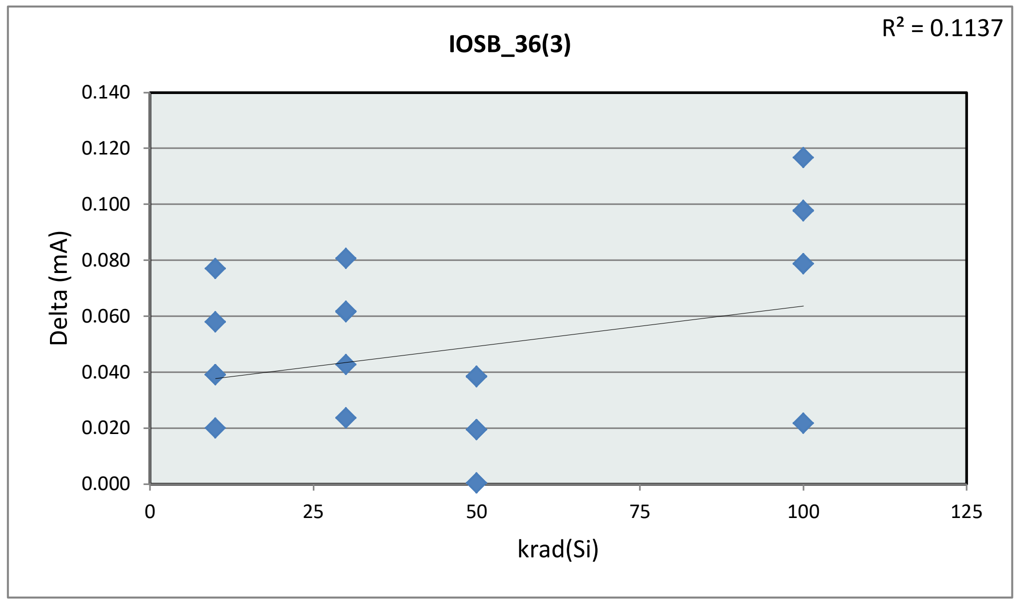


	IOSB_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.262	-4.121	-4.236	-4.172
Average	-3.977	-3.981	-4.007	-4.093
Max	-3.769	-3.778	-3.801	-4.019
UL	8.000	8.000	8.000	8.000

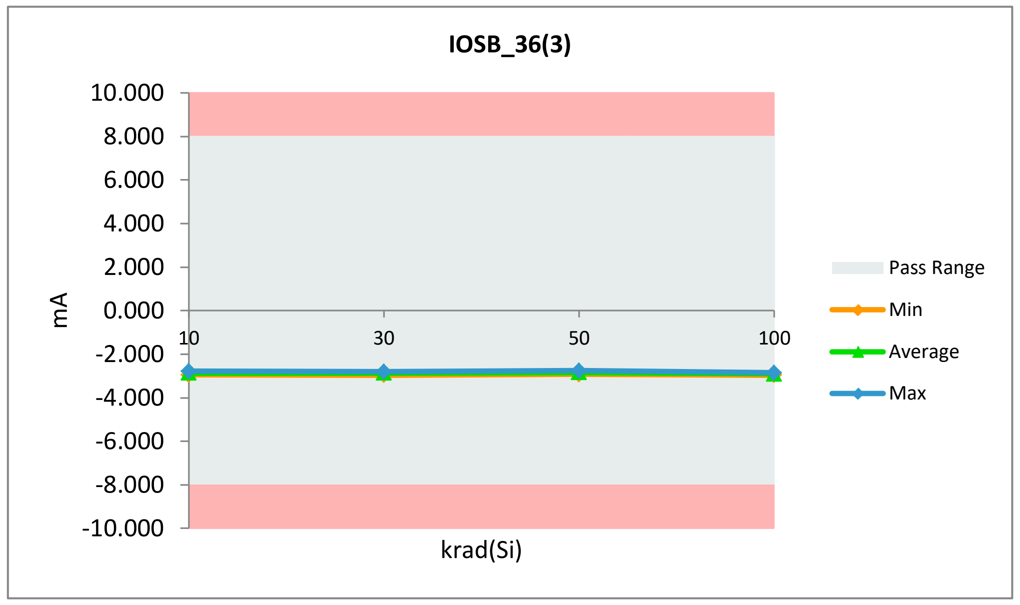


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-2.813	-2.871	0.058
10	5	-2.794	-2.833	0.039
10	7	-2.756	-2.776	0.020
10	11	-2.851	-2.890	0.039
10	15	-2.775	-2.852	0.077
10	20	-2.870	-2.928	0.058
10	21	-2.756	-2.795	0.039
10	24	-2.908	-2.947	0.039
30	1	-2.813	-2.894	0.081
30	5	-2.794	-2.856	0.062
30	7	-2.756	-2.799	0.043
30	11	-2.851	-2.875	0.024
30	15	-2.775	-2.837	0.062
30	20	-2.870	-2.894	0.024
30	21	-2.756	-2.818	0.062
30	24	-2.908	-2.970	0.062
50	1	-2.813	-2.852	0.038
50	5	-2.794	-2.833	0.038
50	7	-2.756	-2.757	0.000
50	11	-2.851	-2.871	0.019
50	15	-2.775	-2.814	0.038
50	20	-2.870	-2.871	0.000
50	21	-2.756	-2.776	0.019
50	24	-2.908	-2.928	0.019
100	3	-2.813	-2.892	0.079
100	8	-2.870	-2.949	0.079
100	12	-2.832	-2.854	0.022
100	13	-2.870	-2.968	0.098
100	16	-2.832	-2.911	0.079
100	17	-2.756	-2.854	0.098
100	18	-2.775	-2.892	0.117
100	19	-2.832	-2.854	0.022
	Max	-2.756	-2.757	0.117
	Average	-2.818	-2.866	0.048
	Min	-2.908	-2.970	0.000
	Std Dev	0.050	0.055	0.029

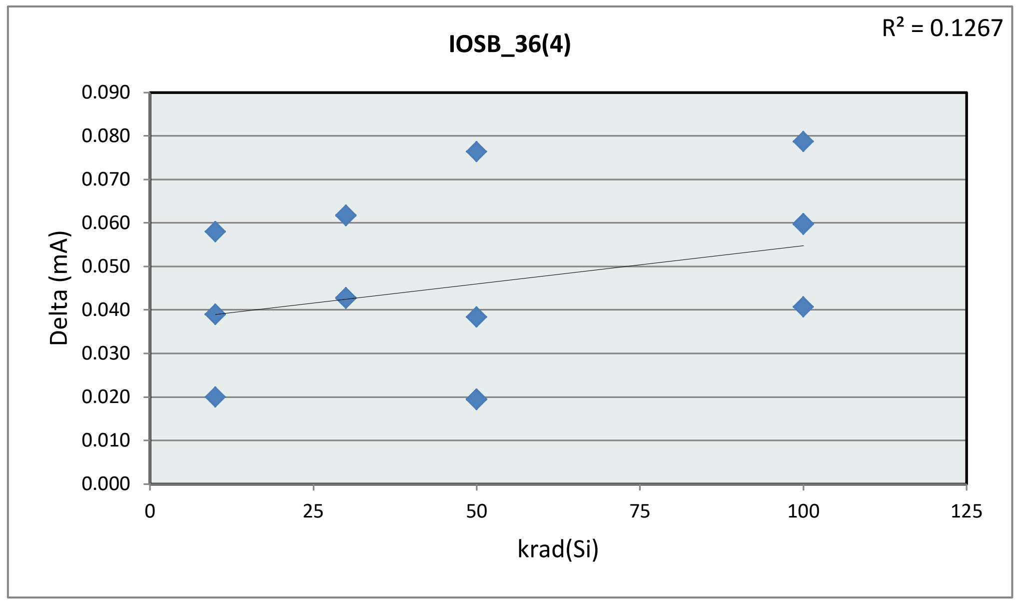


	IOSB_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.947	-2.970	-2.928	-2.968
Average	-2.862	-2.868	-2.838	-2.897
Max	-2.776	-2.799	-2.757	-2.854
UL	8.000	8.000	8.000	8.000

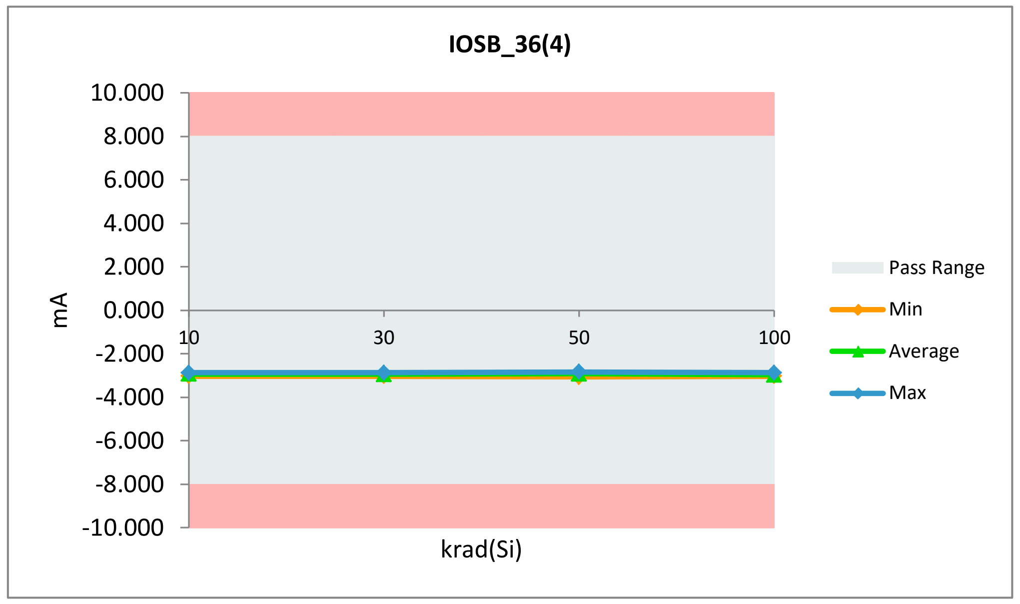


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-2.908	-2.947	0.039
10	5	-2.870	-2.928	0.058
10	7	-2.813	-2.871	0.058
10	11	-2.927	-2.947	0.020
10	15	-2.870	-2.909	0.039
10	20	-2.927	-2.966	0.039
10	21	-2.832	-2.871	0.039
10	24	-2.984	-3.023	0.039
30	1	-2.908	-2.951	0.043
30	5	-2.870	-2.932	0.062
30	7	-2.813	-2.875	0.062
30	11	-2.927	-2.970	0.043
30	15	-2.870	-2.913	0.043
30	20	-2.927	-2.989	0.062
30	21	-2.832	-2.875	0.043
30	24	-2.984	-3.027	0.043
50	1	-2.908	-2.928	0.019
50	5	-2.870	-2.890	0.019
50	7	-2.813	-2.833	0.019
50	11	-2.927	-2.947	0.019
50	15	-2.870	-2.890	0.019
50	20	-2.927	-2.966	0.038
50	21	-2.832	-2.871	0.038
50	24	-2.984	-3.061	0.076
100	3	-2.889	-2.949	0.060
100	8	-2.946	-3.006	0.060
100	12	-2.908	-2.968	0.060
100	13	-2.965	-3.025	0.060
100	16	-2.889	-2.968	0.079
100	17	-2.832	-2.873	0.041
100	18	-2.870	-2.930	0.060
100	19	-2.927	-2.987	0.060
	Max	-2.813	-2.833	0.079
	Average	-2.895	-2.940	0.046
	Min	-2.984	-3.061	0.019
	Std Dev	0.051	0.055	0.017

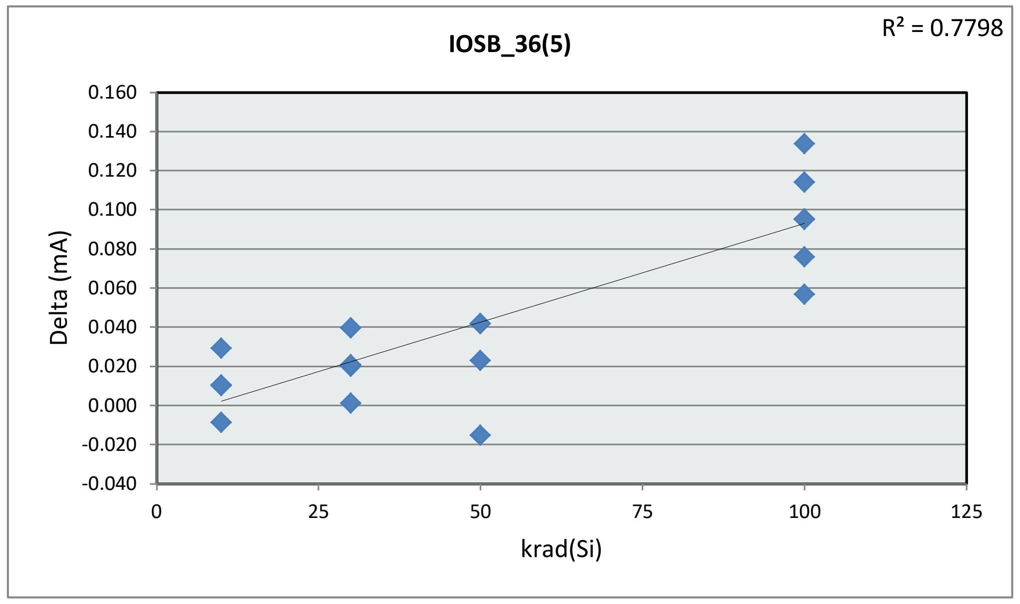


	IOSB_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.023	-3.027	-3.061	-3.025
Average	-2.933	-2.942	-2.923	-2.963
Max	-2.871	-2.875	-2.833	-2.873
UL	8.000	8.000	8.000	8.000

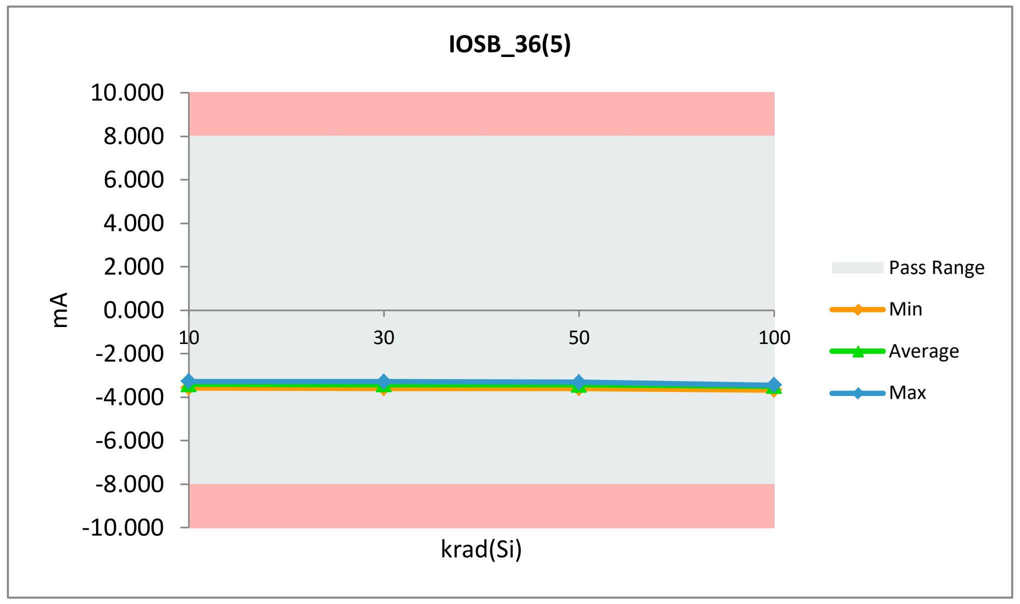


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-3.383	-3.393	0.010
10	5	-3.269	-3.279	0.010
10	7	-3.307	-3.298	-0.009
10	11	-3.497	-3.507	0.010
10	15	-3.364	-3.355	-0.009
10	20	-3.554	-3.565	0.010
10	21	-3.364	-3.374	0.010
10	24	-3.497	-3.526	0.029
30	1	-3.383	-3.403	0.020
30	5	-3.269	-3.289	0.020
30	7	-3.307	-3.327	0.020
30	11	-3.497	-3.537	0.040
30	15	-3.364	-3.365	0.001
30	20	-3.554	-3.594	0.040
30	21	-3.364	-3.384	0.020
30	24	-3.497	-3.518	0.021
50	1	-3.383	-3.425	0.042
50	5	-3.269	-3.311	0.042
50	7	-3.307	-3.349	0.042
50	11	-3.497	-3.482	-0.015
50	15	-3.364	-3.387	0.023
50	20	-3.554	-3.596	0.042
50	21	-3.364	-3.406	0.042
50	24	-3.497	-3.539	0.042
100	3	-3.345	-3.440	0.095
100	8	-3.402	-3.478	0.076
100	12	-3.345	-3.459	0.114
100	13	-3.535	-3.669	0.134
100	16	-3.383	-3.478	0.095
100	17	-3.345	-3.440	0.095
100	18	-3.440	-3.497	0.057
100	19	-3.345	-3.459	0.114
	Max	-3.269	-3.279	0.134
	Average	-3.401	-3.442	0.040
	Min	-3.554	-3.669	-0.015
	Std Dev	0.089	0.098	0.039

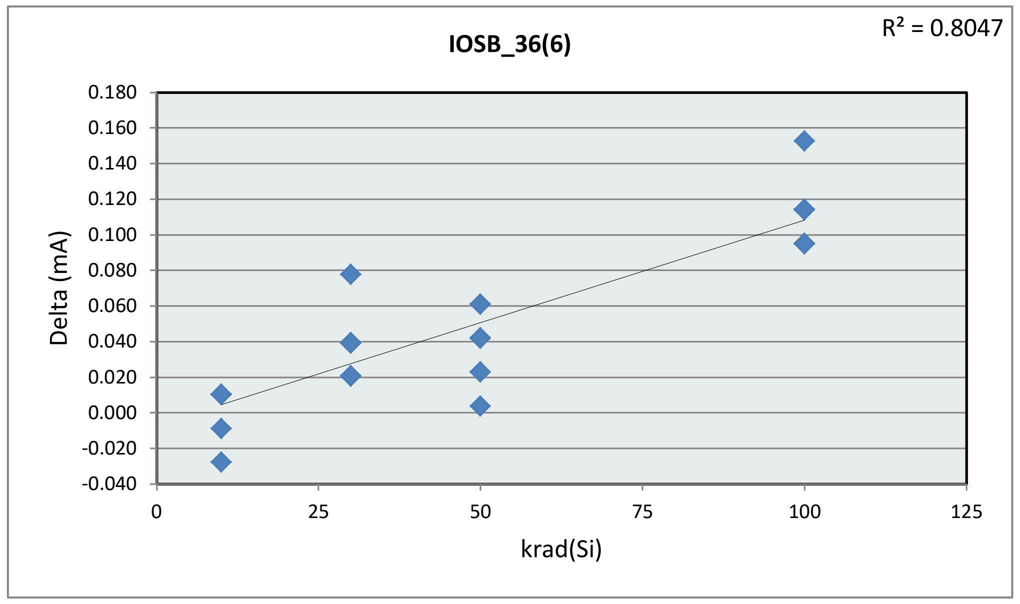


	IOSB_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.565	-3.594	-3.596	-3.669
Average	-3.412	-3.427	-3.437	-3.490
Max	-3.279	-3.289	-3.311	-3.440
UL	8.000	8.000	8.000	8.000

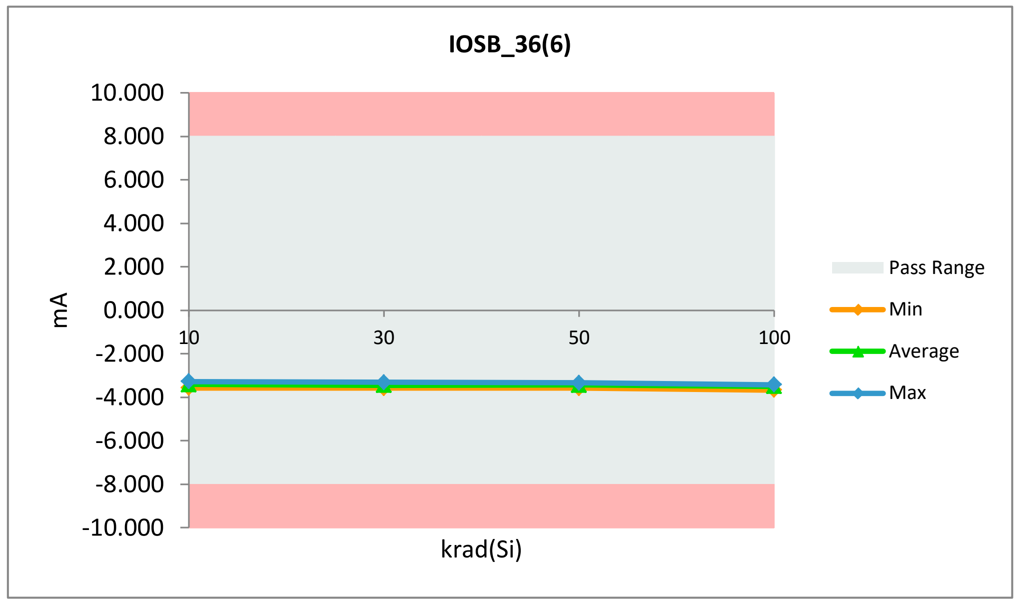


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-3.383	-3.393	0.010
10	5	-3.269	-3.279	0.010
10	7	-3.307	-3.317	0.010
10	11	-3.459	-3.450	-0.009
10	15	-3.345	-3.355	0.010
10	20	-3.554	-3.565	0.010
10	21	-3.364	-3.374	0.010
10	24	-3.535	-3.507	-0.028
30	1	-3.383	-3.422	0.039
30	5	-3.269	-3.308	0.039
30	7	-3.307	-3.346	0.039
30	11	-3.459	-3.537	0.078
30	15	-3.345	-3.384	0.039
30	20	-3.554	-3.575	0.021
30	21	-3.364	-3.403	0.039
30	24	-3.535	-3.556	0.021
50	1	-3.383	-3.425	0.042
50	5	-3.269	-3.330	0.061
50	7	-3.307	-3.330	0.023
50	11	-3.459	-3.501	0.042
50	15	-3.345	-3.406	0.061
50	20	-3.554	-3.577	0.023
50	21	-3.364	-3.406	0.042
50	24	-3.535	-3.539	0.004
100	3	-3.345	-3.440	0.095
100	8	-3.402	-3.516	0.114
100	12	-3.345	-3.459	0.114
100	13	-3.516	-3.669	0.153
100	16	-3.383	-3.497	0.114
100	17	-3.326	-3.421	0.095
100	18	-3.421	-3.516	0.095
100	19	-3.364	-3.478	0.114
	Max	-3.269	-3.279	0.153
	Average	-3.398	-3.446	0.048
	Min	-3.554	-3.669	-0.028
	Std Dev	0.091	0.094	0.044

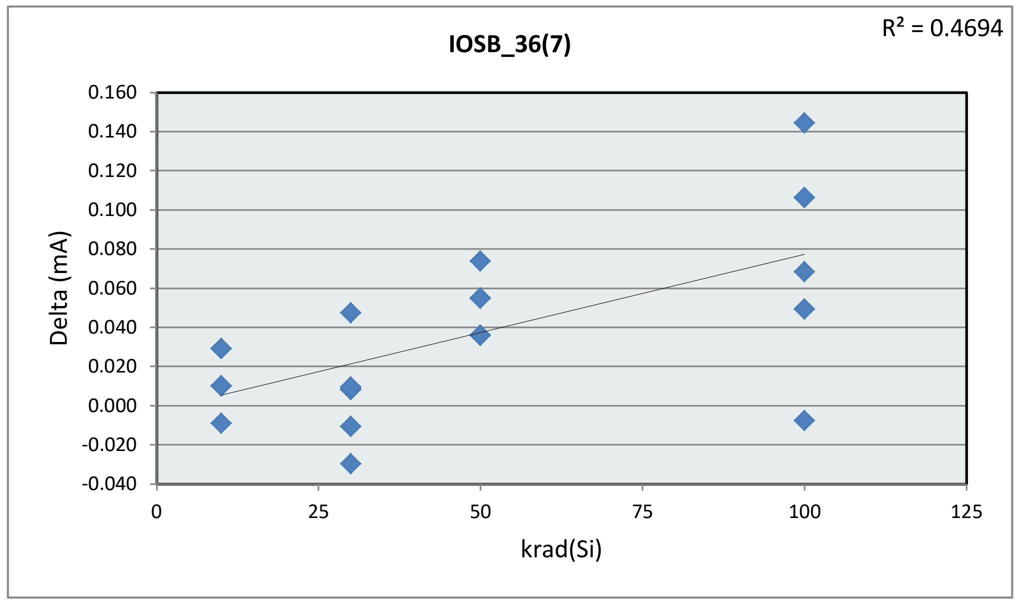


	IOSB_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.565	-3.575	-3.577	-3.669
Average	-3.405	-3.441	-3.439	-3.500
Max	-3.279	-3.308	-3.330	-3.421
UL	8.000	8.000	8.000	8.000

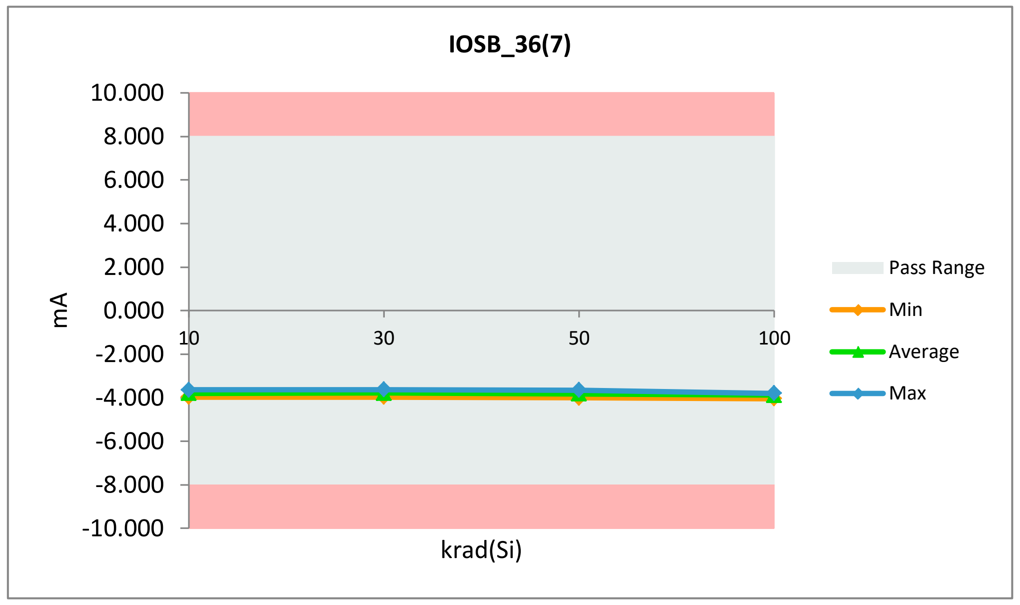


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-3.746	-3.756	0.010
10	5	-3.632	-3.642	0.010
10	7	-3.613	-3.642	0.029
10	11	-3.898	-3.889	-0.009
10	15	-3.803	-3.813	0.010
10	20	-3.917	-3.946	0.029
10	21	-3.689	-3.718	0.029
10	24	-3.955	-3.965	0.010
30	1	-3.746	-3.735	-0.011
30	5	-3.632	-3.640	0.008
30	7	-3.613	-3.621	0.008
30	11	-3.898	-3.868	-0.030
30	15	-3.803	-3.811	0.008
30	20	-3.917	-3.964	0.047
30	21	-3.689	-3.678	-0.011
30	24	-3.955	-3.964	0.009
50	1	-3.746	-3.782	0.036
50	5	-3.632	-3.668	0.036
50	7	-3.613	-3.649	0.036
50	11	-3.898	-3.934	0.036
50	15	-3.803	-3.839	0.036
50	20	-3.917	-3.990	0.074
50	21	-3.689	-3.744	0.055
50	24	-3.955	-4.009	0.055
100	3	-3.765	-3.833	0.068
100	8	-3.841	-3.947	0.106
100	12	-3.746	-3.890	0.144
100	13	-3.993	-4.042	0.049
100	16	-3.784	-3.890	0.106
100	17	-3.708	-3.814	0.106
100	18	-3.803	-3.795	-0.008
100	19	-3.803	-3.852	0.049
	Max	-3.613	-3.621	0.144
	Average	-3.787	-3.823	0.035
	Min	-3.993	-4.042	-0.030
	Std Dev	0.117	0.124	0.040

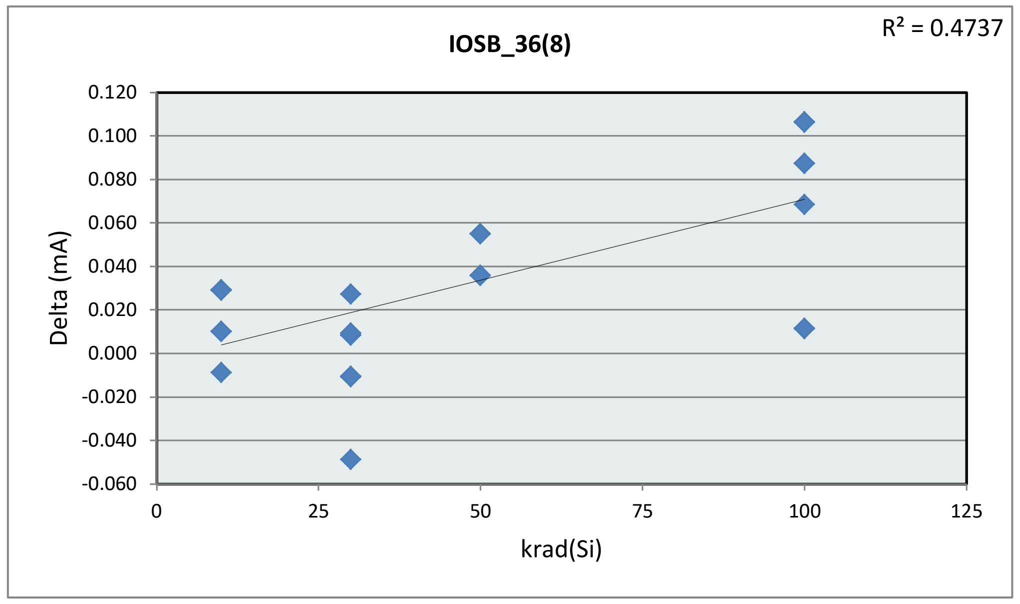


	IOSB_36(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.965	-3.964	-4.009	-4.042
Average	-3.796	-3.785	-3.827	-3.883
Max	-3.642	-3.621	-3.649	-3.795
UL	8.000	8.000	8.000	8.000

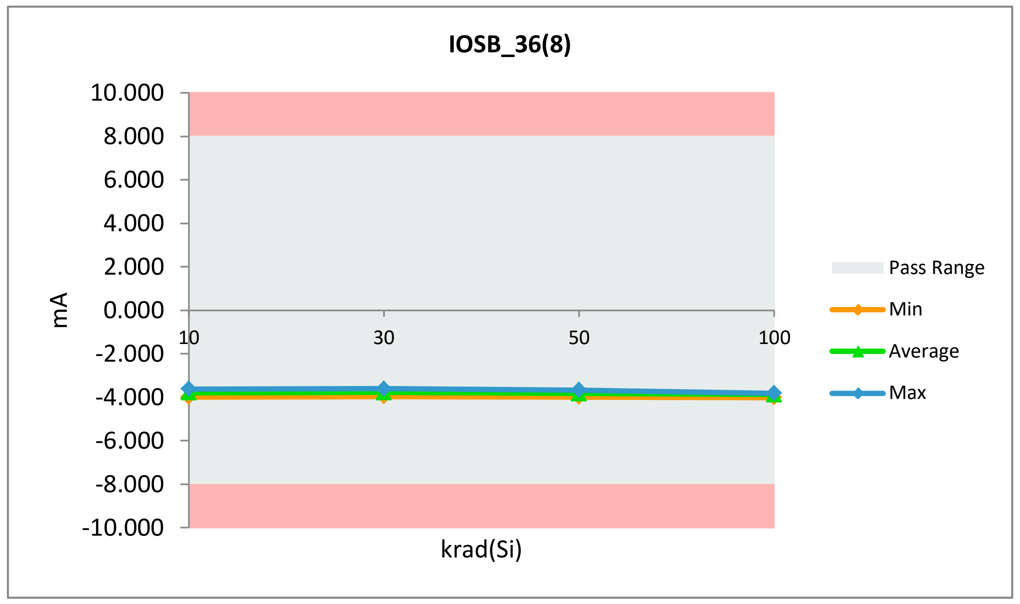


LDR Biased TID Report
SN55LVCP22A-SP

		IOSB_36(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-3.746	-3.737	-0.009
10	5	-3.632	-3.642	0.010
10	7	-3.613	-3.623	0.010
10	11	-3.879	-3.908	0.029
10	15	-3.803	-3.813	0.010
10	20	-3.936	-3.946	0.010
10	21	-3.670	-3.699	0.029
10	24	-3.955	-3.984	0.029
30	1	-3.746	-3.754	0.008
30	5	-3.632	-3.621	-0.011
30	7	-3.613	-3.602	-0.011
30	11	-3.879	-3.830	-0.049
30	15	-3.803	-3.811	0.008
30	20	-3.936	-3.925	-0.011
30	21	-3.670	-3.697	0.027
30	24	-3.955	-3.964	0.009
50	1	-3.746	-3.782	0.036
50	5	-3.632	-3.687	0.055
50	7	-3.613	-3.668	0.055
50	11	-3.879	-3.934	0.055
50	15	-3.803	-3.839	0.036
50	20	-3.936	-3.971	0.036
50	21	-3.670	-3.725	0.055
50	24	-3.955	-3.990	0.036
100	3	-3.765	-3.852	0.087
100	8	-3.860	-3.928	0.068
100	12	-3.746	-3.852	0.106
100	13	-3.993	-4.004	0.011
100	16	-3.784	-3.890	0.106
100	17	-3.727	-3.814	0.087
100	18	-3.803	-3.814	0.011
100	19	-3.803	-3.890	0.087
	Max	-3.613	-3.602	0.106
	Average	-3.787	-3.819	0.032
	Min	-3.993	-4.004	-0.049
	Std Dev	0.119	0.121	0.037



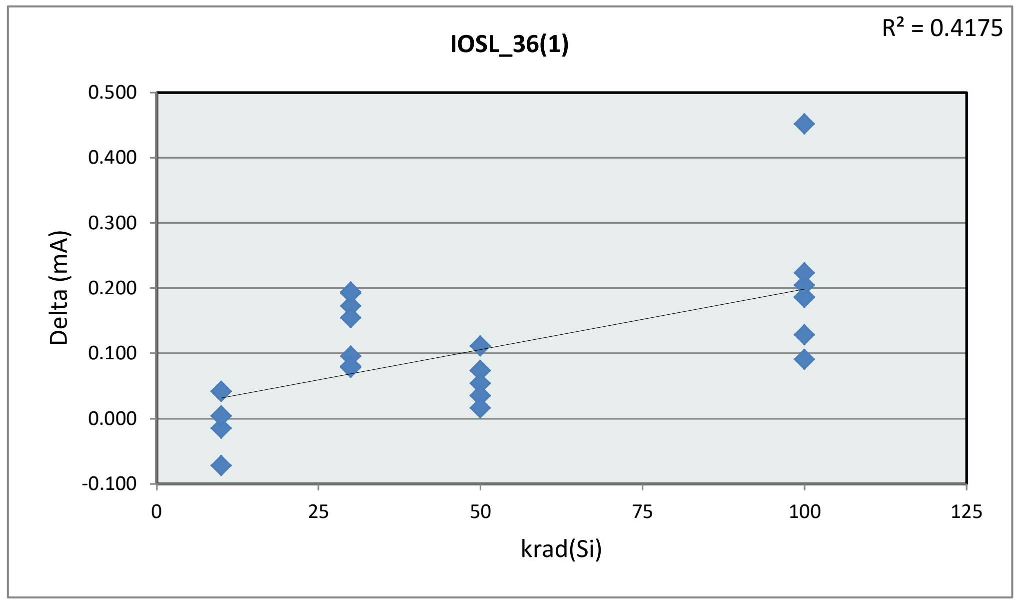
	IOSB_36(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.984	-3.964	-3.990	-4.004
Average	-3.794	-3.776	-3.824	-3.881
Max	-3.623	-3.602	-3.668	-3.814
UL	8.000	8.000	8.000	8.000



LDR Biased TID Report
SN55LVCP22A-SP

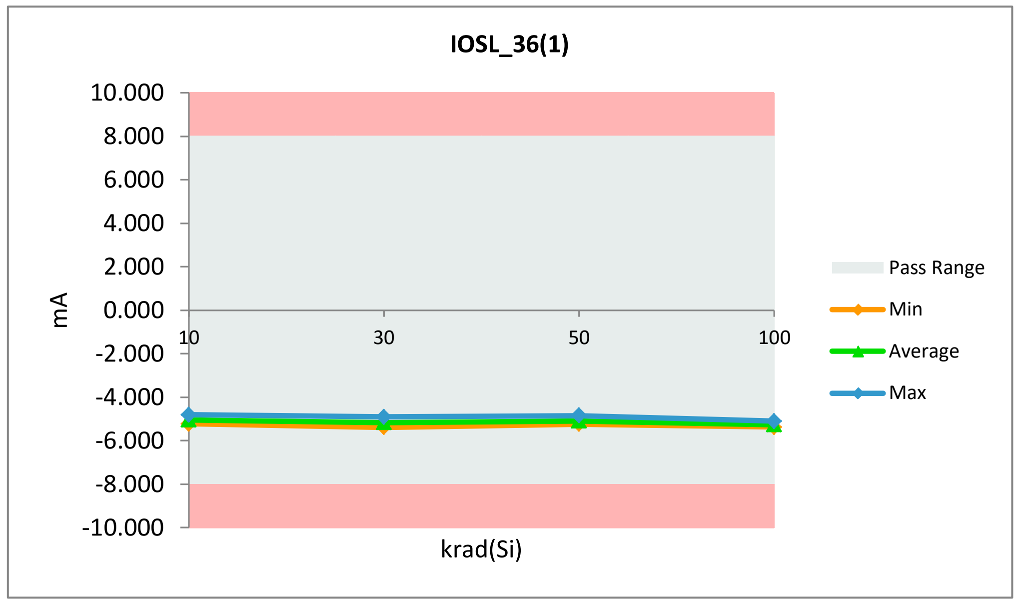
	IOSL_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-5.016	-5.057	0.041
10	5	-4.902	-4.944	0.041
10	7	-4.808	-4.811	0.004
10	11	-5.111	-5.095	-0.015
10	15	-5.054	-5.095	0.041
10	20	-5.186	-5.228	0.041
10	21	-4.940	-4.944	0.004
10	24	-5.224	-5.152	-0.072
30	1	-5.016	-5.208	0.192
30	5	-4.902	-5.075	0.173
30	7	-4.808	-4.903	0.095
30	11	-5.111	-5.265	0.154
30	15	-5.054	-5.132	0.078
30	20	-5.186	-5.380	0.194
30	21	-4.940	-5.018	0.078
30	24	-5.224	-5.304	0.080
50	1	-5.016	-5.127	0.111
50	5	-4.902	-4.975	0.073
50	7	-4.808	-4.843	0.035
50	11	-5.111	-5.165	0.054
50	15	-5.054	-5.127	0.073
50	20	-5.186	-5.241	0.054
50	21	-4.940	-4.975	0.035
50	24	-5.224	-5.241	0.016
100	3	-5.016	-5.201	0.185
100	8	-5.111	-5.296	0.185
100	12	-5.111	-5.201	0.090
100	13	-5.186	-5.373	0.187
100	16	-5.130	-5.334	0.204
100	17	-4.978	-5.106	0.128
100	18	-4.997	-5.220	0.223
100	19	-4.921	-5.373	0.452
	Max	-4.808	-4.811	0.452
	Average	-5.037	-5.138	0.101
	Min	-5.224	-5.380	-0.072
	Std Dev	0.126	0.154	0.098



	IOSL_36(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.228	-5.380	-5.241	-5.373
Average	-5.041	-5.161	-5.087	-5.263
Max	-4.811	-4.903	-4.843	-5.106
UL	8.000	8.000	8.000	8.000



LDR Biased TID Report
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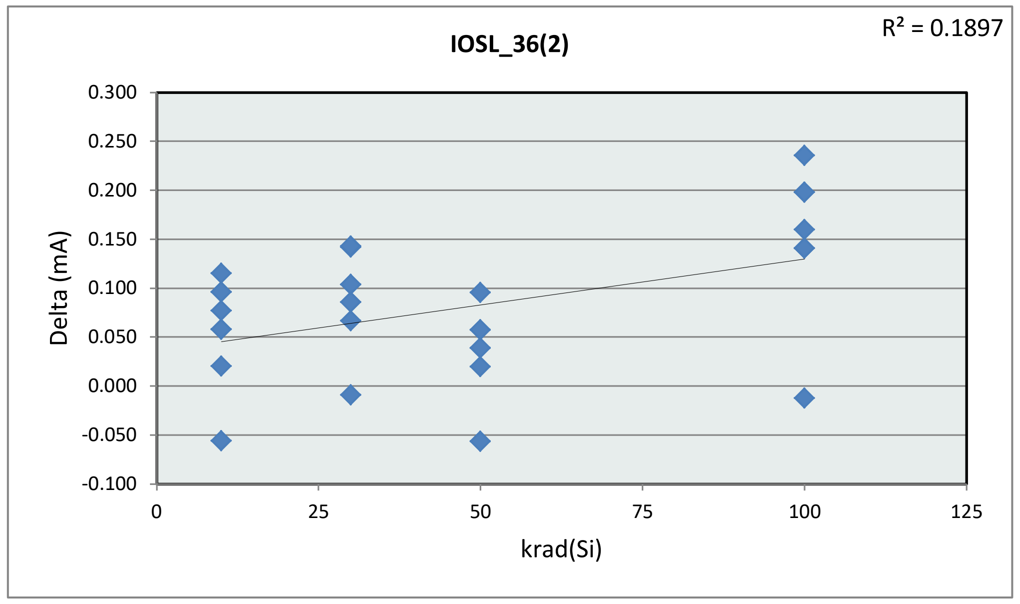
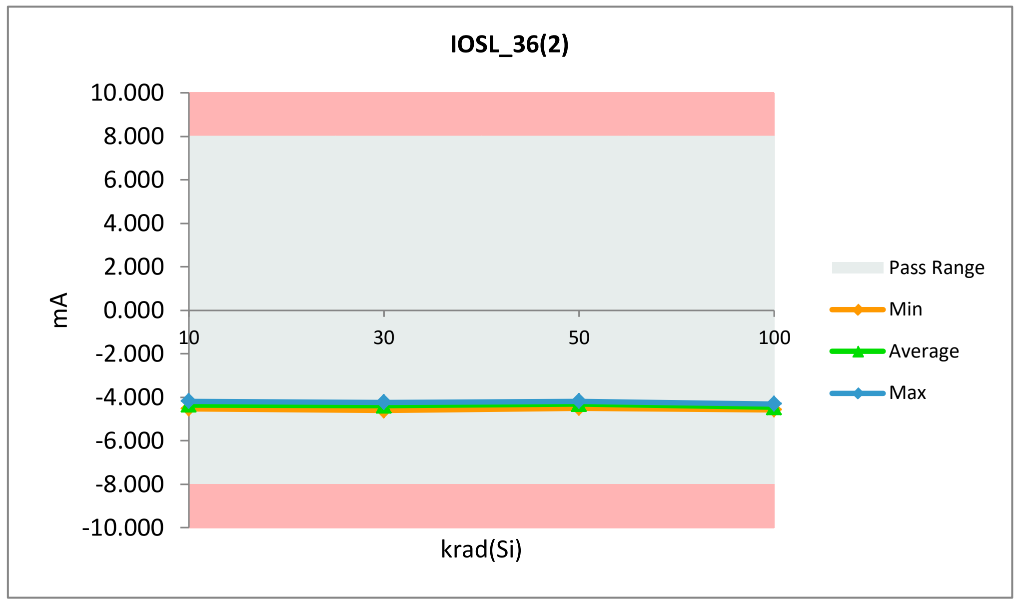
	IOSL_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.294	-4.409	0.115
10	5	-4.199	-4.295	0.096
10	7	-4.085	-4.181	0.096
10	11	-4.351	-4.409	0.058
10	15	-4.313	-4.333	0.020
10	20	-4.484	-4.428	-0.056
10	21	-4.180	-4.257	0.077
10	24	-4.465	-4.523	0.058
30	1	-4.294	-4.380	0.086
30	5	-4.199	-4.303	0.104
30	7	-4.085	-4.227	0.142
30	11	-4.351	-4.437	0.086
30	15	-4.313	-4.380	0.067
30	20	-4.484	-4.475	-0.009
30	21	-4.180	-4.284	0.104
30	24	-4.465	-4.608	0.143
50	1	-4.294	-4.333	0.039
50	5	-4.199	-4.257	0.057
50	7	-4.085	-4.181	0.095
50	11	-4.351	-4.295	-0.056
50	15	-4.313	-4.333	0.020
50	20	-4.484	-4.428	-0.056
50	21	-4.180	-4.238	0.057
50	24	-4.465	-4.504	0.039
100	3	-4.275	-4.435	0.160
100	8	-4.351	-4.492	0.141
100	12	-4.313	-4.511	0.198
100	13	-4.427	-4.568	0.141
100	16	-4.332	-4.473	0.141
100	17	-4.313	-4.301	-0.012
100	18	-4.256	-4.454	0.198
100	19	-4.237	-4.473	0.236
	Max	-4.085	-4.181	0.236
	Average	-4.301	-4.381	0.081
	Min	-4.484	-4.608	-0.056
	Std Dev	0.118	0.113	0.073



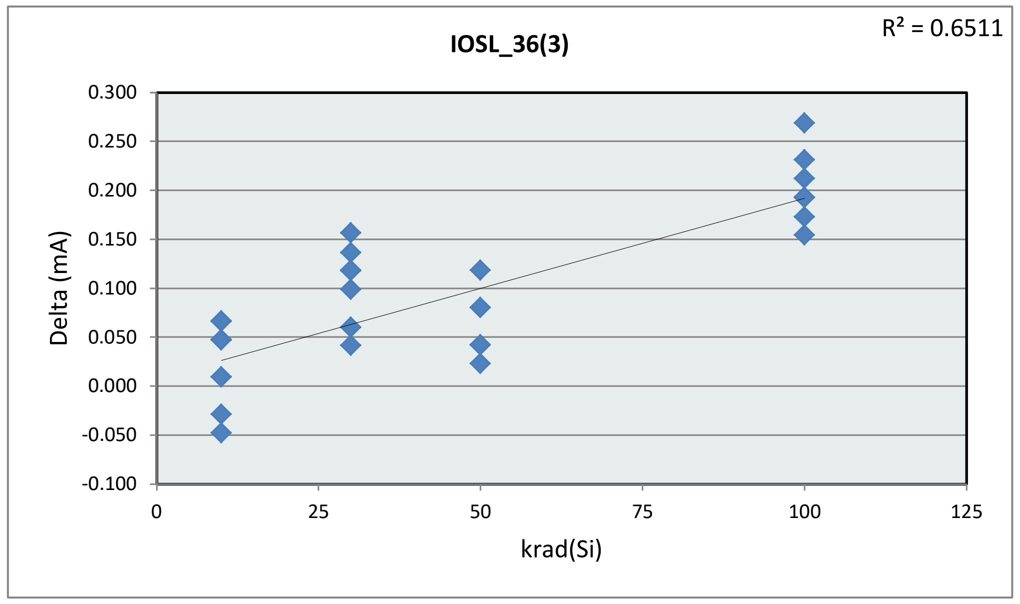
	IOSL_36(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.523	-4.608	-4.504	-4.568
Average	-4.355	-4.387	-4.321	-4.463
Max	-4.181	-4.227	-4.181	-4.301
UL	8.000	8.000	8.000	8.000

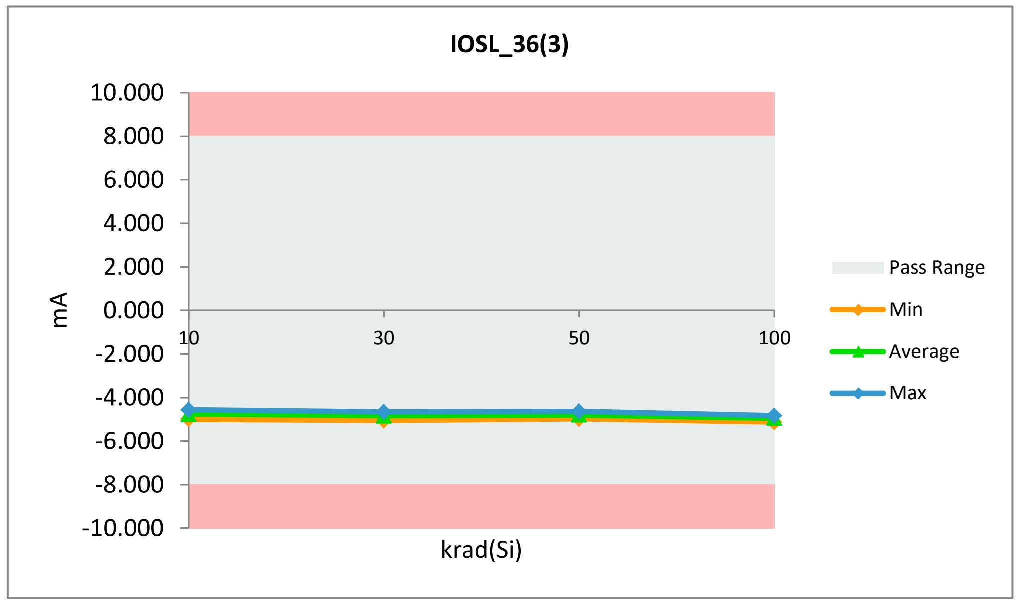


LDR Biased TID Report
SN55LVCP22A-SP

		IOSL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.773	-4.726	-0.048
10	5	-4.526	-4.592	0.067
10	7	-4.602	-4.573	-0.029
10	11	-4.888	-4.897	0.009
10	15	-4.678	-4.726	0.047
10	20	-4.907	-4.973	0.066
10	21	-4.640	-4.649	0.009
10	24	-4.945	-4.992	0.047
30	1	-4.773	-4.815	0.042
30	5	-4.526	-4.662	0.136
30	7	-4.602	-4.662	0.060
30	11	-4.888	-4.948	0.060
30	15	-4.678	-4.796	0.118
30	20	-4.907	-5.063	0.156
30	21	-4.640	-4.739	0.099
30	24	-4.945	-5.063	0.118
50	1	-4.773	-4.815	0.042
50	5	-4.526	-4.644	0.118
50	7	-4.602	-4.644	0.042
50	11	-4.888	-4.911	0.023
50	15	-4.678	-4.758	0.080
50	20	-4.907	-4.987	0.080
50	21	-4.640	-4.682	0.042
50	24	-4.945	-4.987	0.042
100	3	-4.678	-4.871	0.193
100	8	-4.831	-5.023	0.192
100	12	-4.659	-4.871	0.212
100	13	-4.907	-5.138	0.231
100	16	-4.773	-4.966	0.193
100	17	-4.659	-4.832	0.173
100	18	-4.773	-4.928	0.155
100	19	-4.659	-4.928	0.269
	Max	-4.526	-4.573	0.269
	Average	-4.744	-4.839	0.095
	Min	-4.945	-5.138	-0.048
	Std Dev	0.136	0.154	0.078



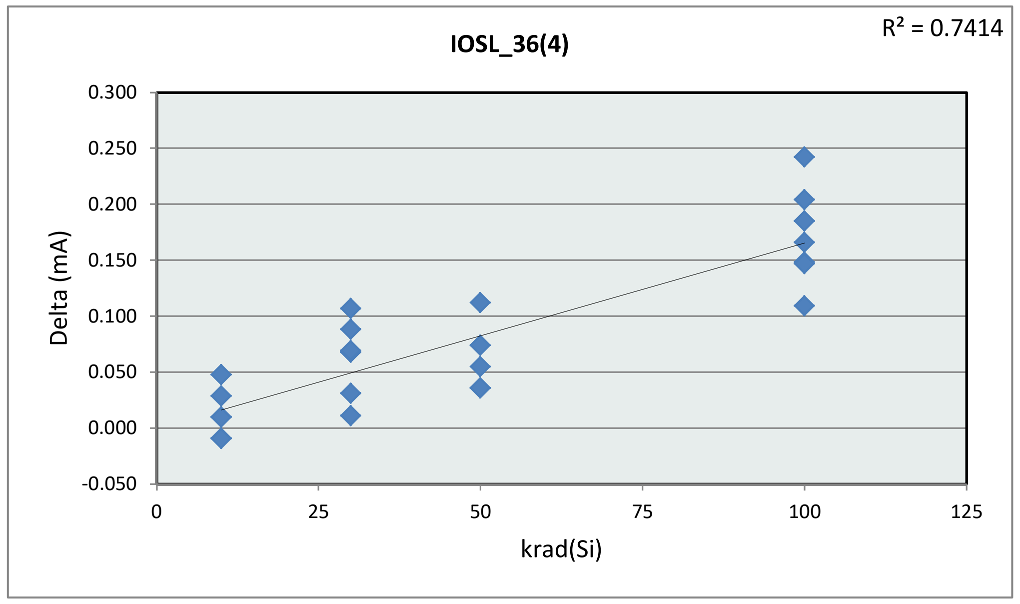
	IOSL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.992	-5.063	-4.987	-5.138
Average	-4.766	-4.844	-4.804	-4.945
Max	-4.573	-4.662	-4.644	-4.832
UL	8.000	8.000	8.000	8.000



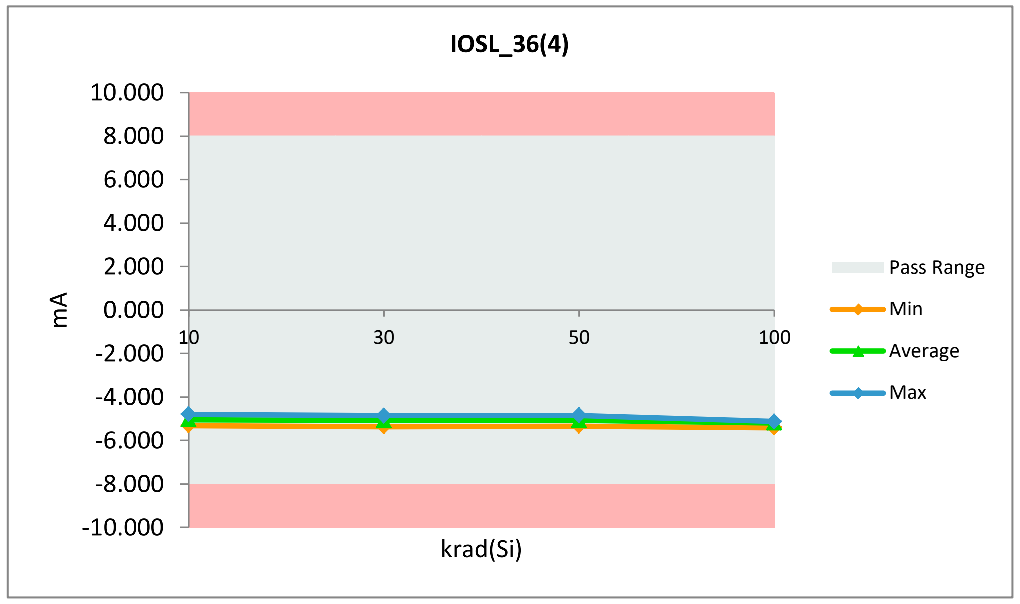
LDR Biased TID Report
SN55LVCP22A-SP

	IOSL_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.980	-5.009	0.029
10	5	-4.790	-4.800	0.010
10	7	-4.809	-4.838	0.029
10	11	-5.151	-5.161	0.010
10	15	-4.980	-5.028	0.048
10	20	-5.265	-5.313	0.048
10	21	-4.885	-4.876	-0.009
10	24	-5.265	-5.256	-0.009
30	1	-4.980	-5.048	0.068
30	5	-4.790	-4.858	0.068
30	7	-4.809	-4.877	0.068
30	11	-5.151	-5.220	0.069
30	15	-4.980	-5.087	0.107
30	20	-5.265	-5.353	0.088
30	21	-4.885	-4.896	0.011
30	24	-5.265	-5.296	0.031
50	1	-4.980	-5.016	0.036
50	5	-4.790	-4.864	0.074
50	7	-4.809	-4.845	0.036
50	11	-5.151	-5.206	0.055
50	15	-4.980	-5.092	0.112
50	20	-5.265	-5.339	0.074
50	21	-4.885	-4.921	0.036
50	24	-5.265	-5.301	0.036
100	3	-4.961	-5.127	0.166
100	8	-5.037	-5.146	0.109
100	12	-4.942	-5.146	0.204
100	13	-5.265	-5.413	0.148
100	16	-4.999	-5.184	0.185
100	17	-4.904	-5.146	0.242
100	18	-5.018	-5.165	0.147
100	19	-4.999	-5.184	0.185
	Max	-4.790	-4.800	0.242
	Average	-5.016	-5.094	0.078
	Min	-5.265	-5.413	-0.009
	Std Dev	0.166	0.176	0.065

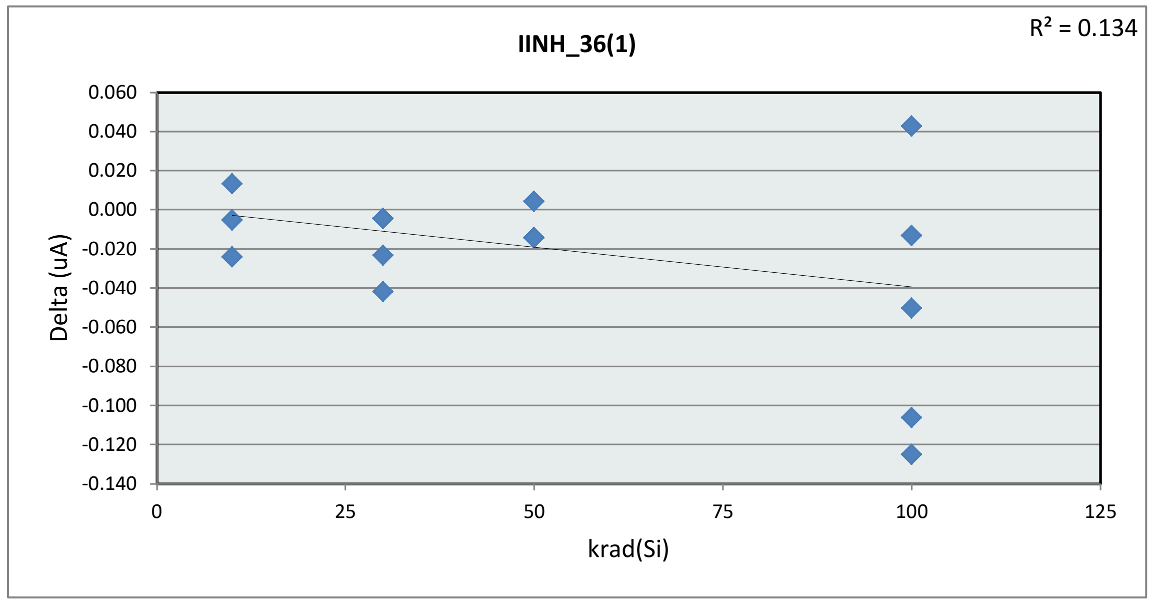


	IOSL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.313	-5.353	-5.339	-5.413
Average	-5.035	-5.079	-5.073	-5.189
Max	-4.800	-4.858	-4.845	-5.127
UL	8.000	8.000	8.000	8.000

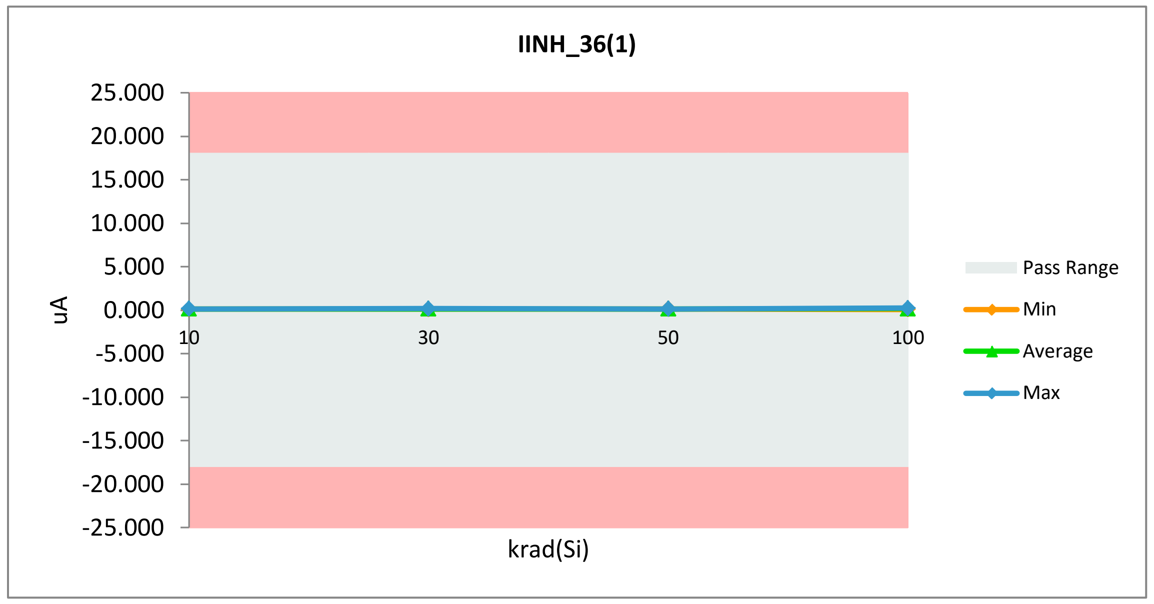


LDR Biased TID Report
SN55LVCP22A-SP

		IINH_36(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.143	0.149	-0.005
10	5	0.125	0.149	-0.024
10	7	0.125	0.130	-0.005
10	11	0.143	0.149	-0.005
10	15	0.143	0.149	-0.005
10	20	0.143	0.130	0.013
10	21	0.125	0.149	-0.024
10	24	0.125	0.130	-0.005
30	1	0.143	0.148	-0.005
30	5	0.125	0.129	-0.005
30	7	0.125	0.129	-0.005
30	11	0.143	0.148	-0.005
30	15	0.143	0.185	-0.042
30	20	0.143	0.148	-0.005
30	21	0.125	0.148	-0.023
30	24	0.125	0.129	-0.005
50	1	0.143	0.139	0.004
50	5	0.125	0.139	-0.014
50	7	0.125	0.139	-0.014
50	11	0.143	0.158	-0.014
50	15	0.143	0.158	-0.014
50	20	0.143	0.139	0.004
50	21	0.125	0.139	-0.014
50	24	0.125	0.139	-0.014
100	3	0.125	0.082	0.043
100	8	0.125	0.175	-0.050
100	12	0.143	0.101	0.043
100	13	0.162	0.175	-0.013
100	16	0.125	0.250	-0.125
100	17	0.125	0.250	-0.125
100	18	0.143	0.250	-0.106
100	19	0.143	0.156	-0.013
	Max	0.162	0.250	0.043
	Average	0.135	0.153	-0.018
	Min	0.125	0.082	-0.125
	Std Dev	0.011	0.037	0.038

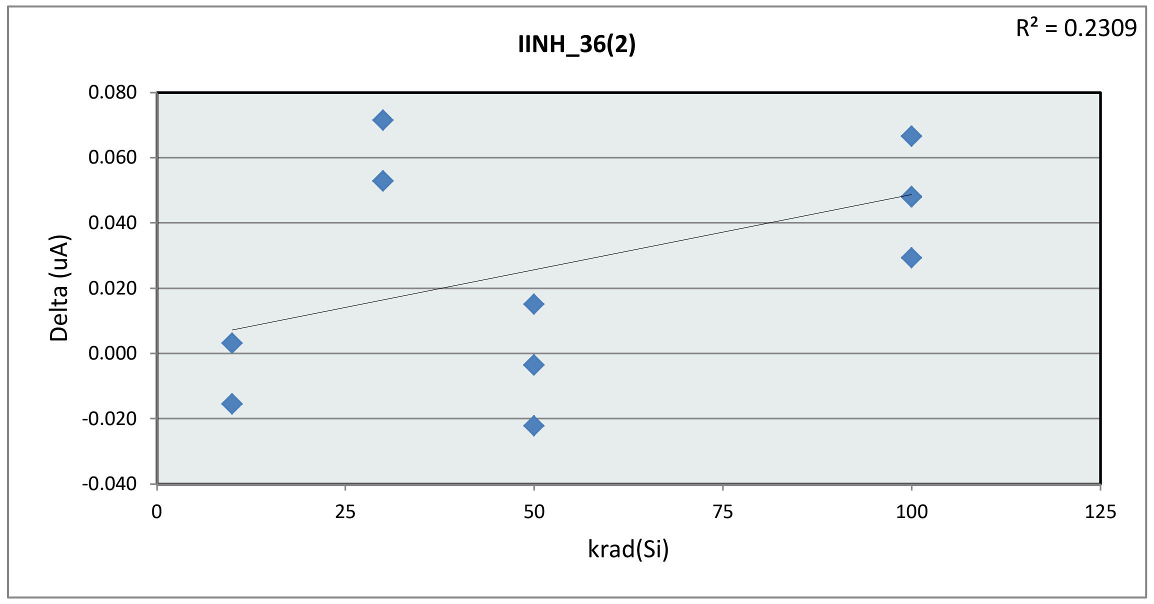


	IINH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.130	0.129	0.139	0.082
Average	0.142	0.146	0.144	0.180
Max	0.149	0.185	0.158	0.250
UL	18.000	18.000	18.000	18.000

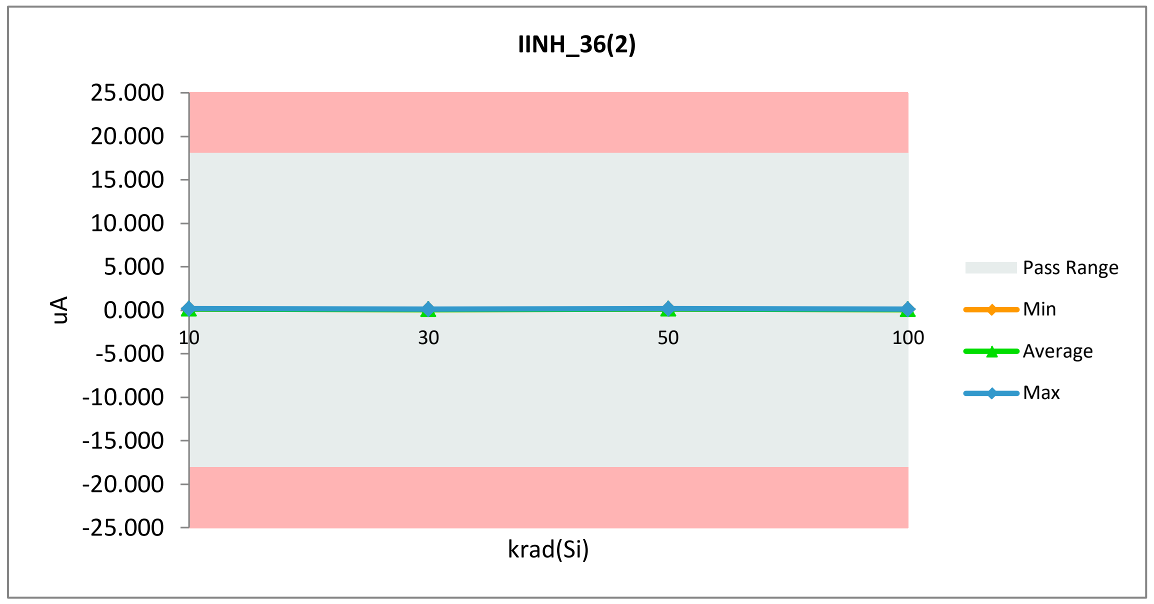


LDR Biased TID Report
SN55LVCP22A-SP

		IINH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.163	0.160	0.003
10	5	0.145	0.160	-0.016
10	7	0.145	0.160	-0.016
10	11	0.163	0.179	-0.016
10	15	0.182	0.179	0.003
10	20	0.163	0.160	0.003
10	21	0.163	0.179	-0.016
10	24	0.145	0.160	-0.016
30	1	0.163	0.111	0.053
30	5	0.145	0.092	0.053
30	7	0.145	0.092	0.053
30	11	0.163	0.111	0.053
30	15	0.182	0.111	0.071
30	20	0.163	0.092	0.071
30	21	0.163	0.111	0.053
30	24	0.145	0.092	0.053
50	1	0.163	0.167	-0.004
50	5	0.145	0.167	-0.022
50	7	0.145	0.148	-0.004
50	11	0.163	0.167	-0.004
50	15	0.182	0.186	-0.004
50	20	0.163	0.148	0.015
50	21	0.163	0.167	-0.004
50	24	0.145	0.148	-0.004
100	3	0.163	0.097	0.067
100	8	0.126	0.097	0.029
100	12	0.163	0.097	0.067
100	13	0.163	0.116	0.048
100	16	0.145	0.097	0.048
100	17	0.126	0.078	0.048
100	18	0.145	0.097	0.048
100	19	0.182	0.116	0.067
	Max	0.182	0.186	0.071
	Average	0.157	0.133	0.024
	Min	0.126	0.078	-0.022
	Std Dev	0.015	0.035	0.033

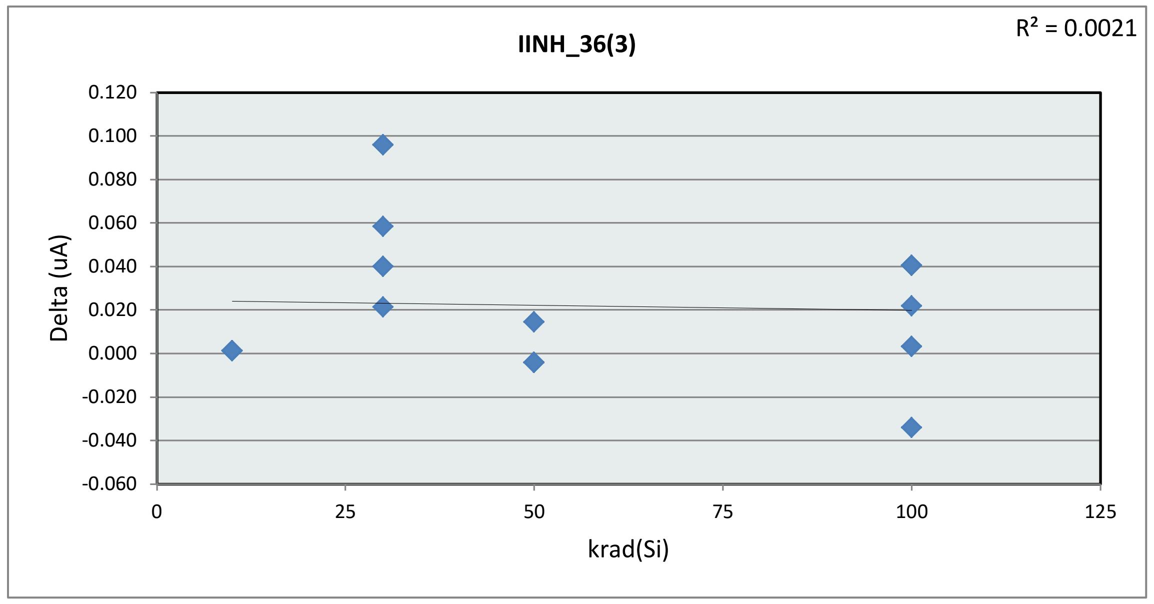


	IINH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.160	0.092	0.148	0.078
Average	0.167	0.101	0.162	0.099
Max	0.179	0.111	0.186	0.116
UL	18.000	18.000	18.000	18.000

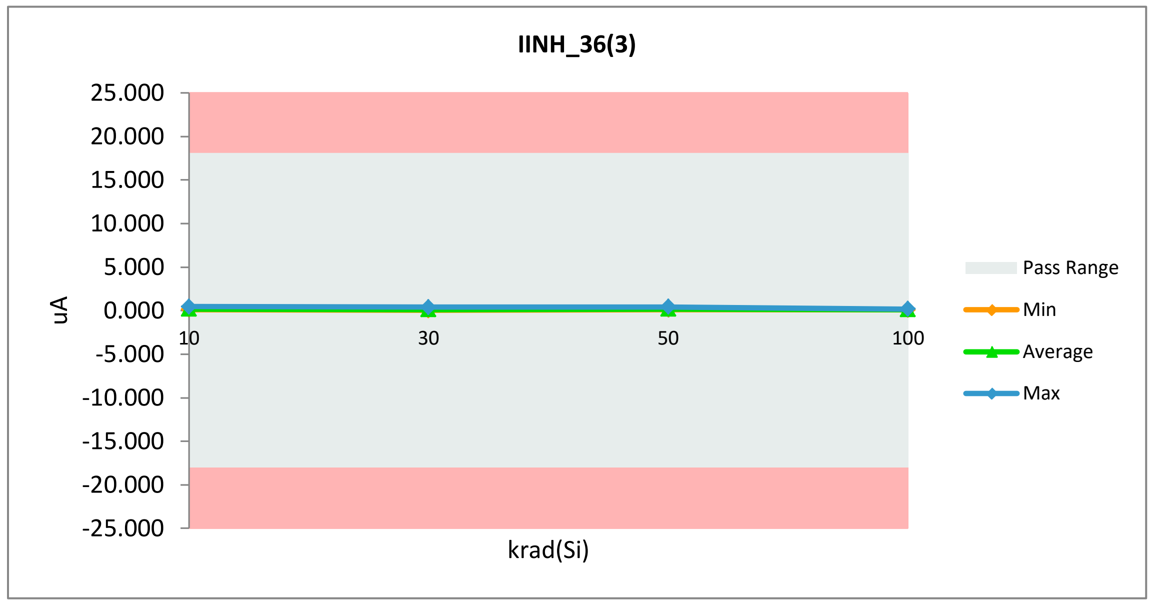


LDR Biased TID Report
SN55LVCP22A-SP

		IINH_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.138	0.137	0.001
10	5	0.138	0.137	0.001
10	7	0.138	0.137	0.001
10	11	0.138	0.137	0.001
10	15	0.157	0.155	0.001
10	20	0.455	0.454	0.001
10	21	0.138	0.137	0.001
10	24	0.119	0.118	0.001
30	1	0.138	0.098	0.040
30	5	0.138	0.042	0.096
30	7	0.138	0.042	0.096
30	11	0.138	0.042	0.096
30	15	0.157	0.061	0.096
30	20	0.455	0.397	0.058
30	21	0.138	0.098	0.040
30	24	0.119	0.098	0.021
50	1	0.138	0.142	-0.004
50	5	0.138	0.142	-0.004
50	7	0.138	0.142	-0.004
50	11	0.138	0.142	-0.004
50	15	0.157	0.142	0.014
50	20	0.455	0.440	0.014
50	21	0.138	0.142	-0.004
50	24	0.119	0.124	-0.004
100	3	0.138	0.135	0.003
100	8	0.119	0.116	0.003
100	12	0.138	0.172	-0.034
100	13	0.138	0.098	0.040
100	16	0.138	0.098	0.040
100	17	0.119	0.079	0.040
100	18	0.138	0.098	0.040
100	19	0.138	0.116	0.022
	Max	0.455	0.454	0.096
	Average	0.167	0.144	0.022
	Min	0.119	0.042	-0.034
	Std Dev	0.095	0.099	0.034



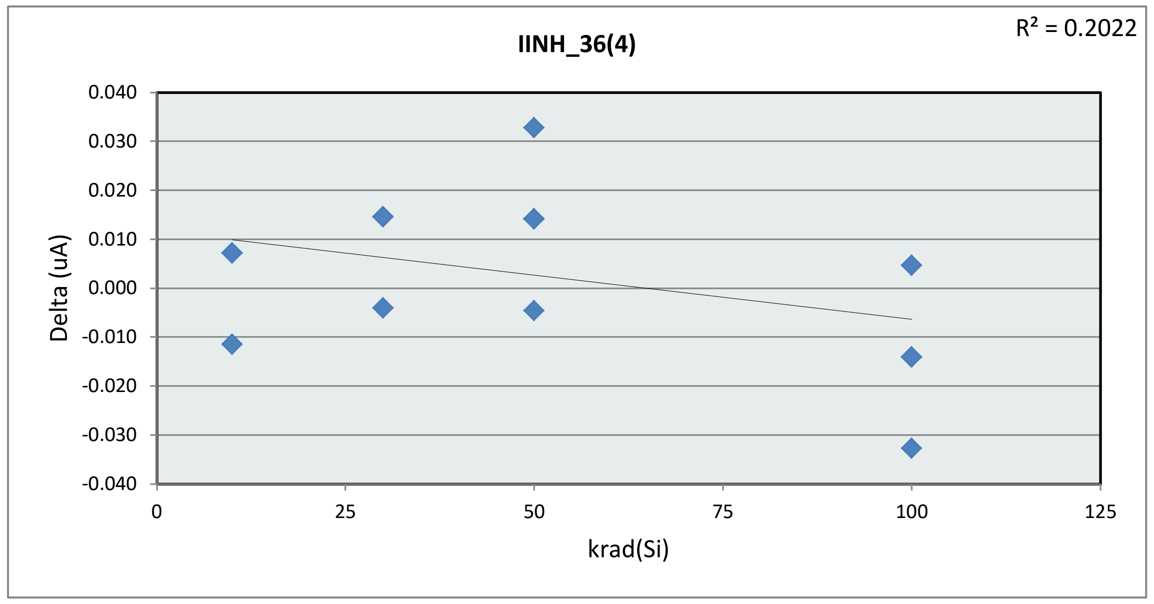
	IINH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.118	0.042	0.124	0.079
Average	0.176	0.110	0.177	0.114
Max	0.454	0.397	0.440	0.172
UL	18.000	18.000	18.000	18.000



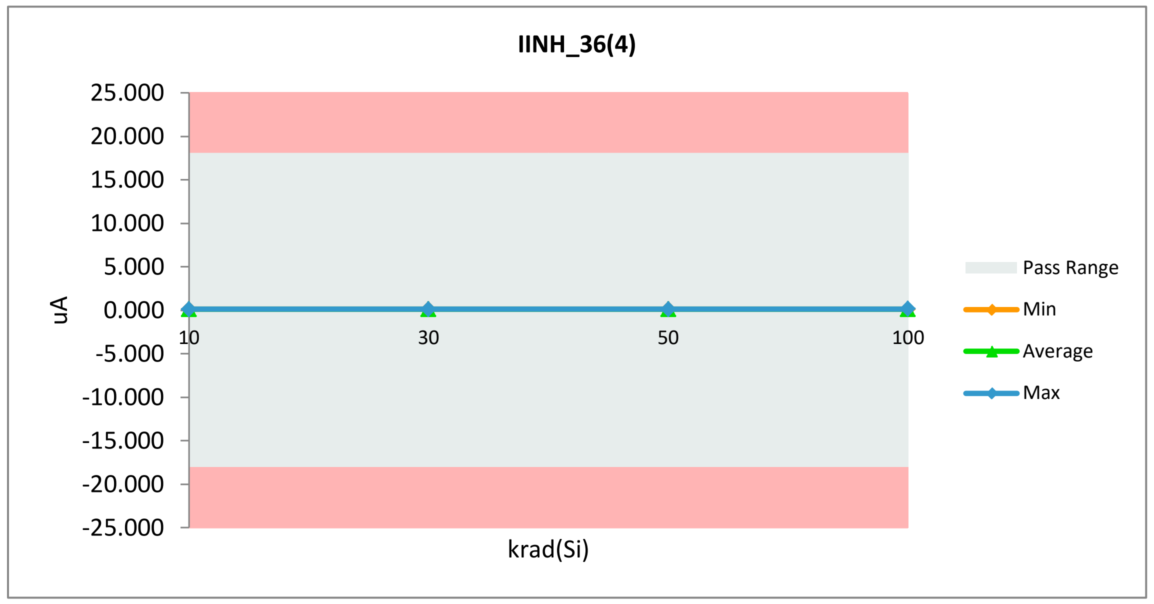
LDR Biased TID Report
SN55LVCP22A-SP

	IINH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.145	0.138	0.007
10	5	0.108	0.119	-0.011
10	7	0.126	0.119	0.007
10	11	0.126	0.119	0.007
10	15	0.126	0.138	-0.011
10	20	0.145	0.138	0.007
10	21	0.126	0.119	0.007
10	24	0.126	0.119	0.007
30	1	0.145	0.130	0.015
30	5	0.108	0.112	-0.004
30	7	0.126	0.112	0.015
30	11	0.126	0.112	0.015
30	15	0.126	0.130	-0.004
30	20	0.145	0.130	0.015
30	21	0.126	0.130	-0.004
30	24	0.126	0.112	0.015
50	1	0.145	0.112	0.033
50	5	0.108	0.112	-0.005
50	7	0.126	0.112	0.014
50	11	0.126	0.112	0.014
50	15	0.126	0.112	0.014
50	20	0.145	0.131	0.014
50	21	0.126	0.112	0.014
50	24	0.126	0.112	0.014
100	3	0.108	0.122	-0.014
100	8	0.108	0.122	-0.014
100	12	0.145	0.140	0.005
100	13	0.126	0.122	0.005
100	16	0.108	0.122	-0.014
100	17	0.108	0.122	-0.014
100	18	0.108	0.140	-0.033
100	19	0.126	0.140	-0.014
	Max	0.145	0.140	0.033
	Average	0.126	0.123	0.003
	Min	0.108	0.112	-0.033
	Std Dev	0.013	0.010	0.014

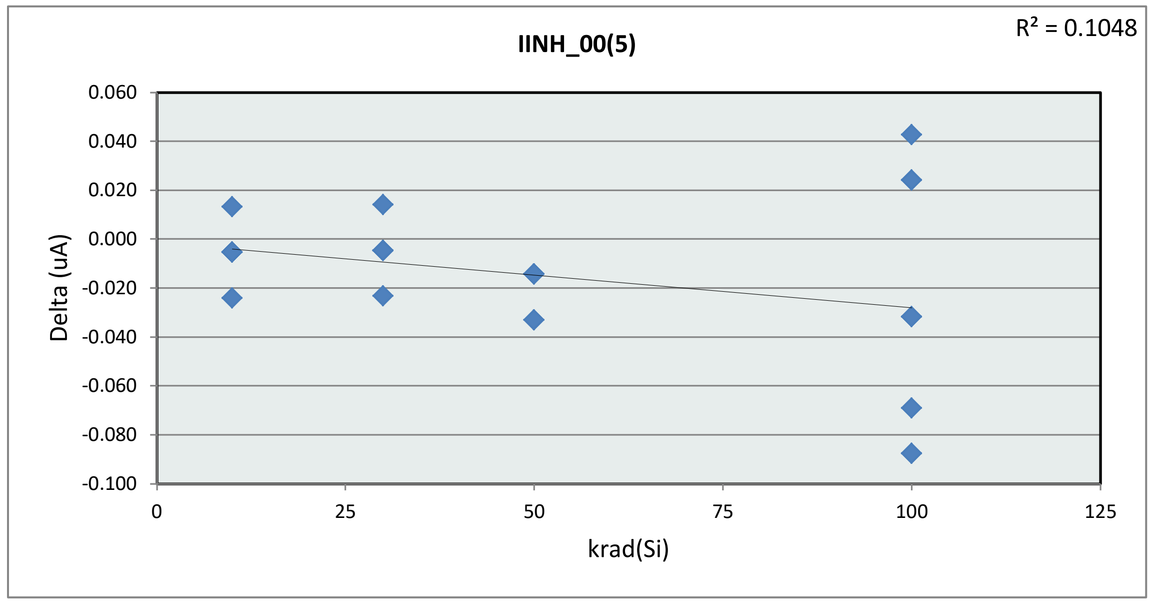


	IINH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.119	0.112	0.112	0.122
Average	0.126	0.121	0.115	0.129
Max	0.138	0.130	0.131	0.140
UL	18.000	18.000	18.000	18.000

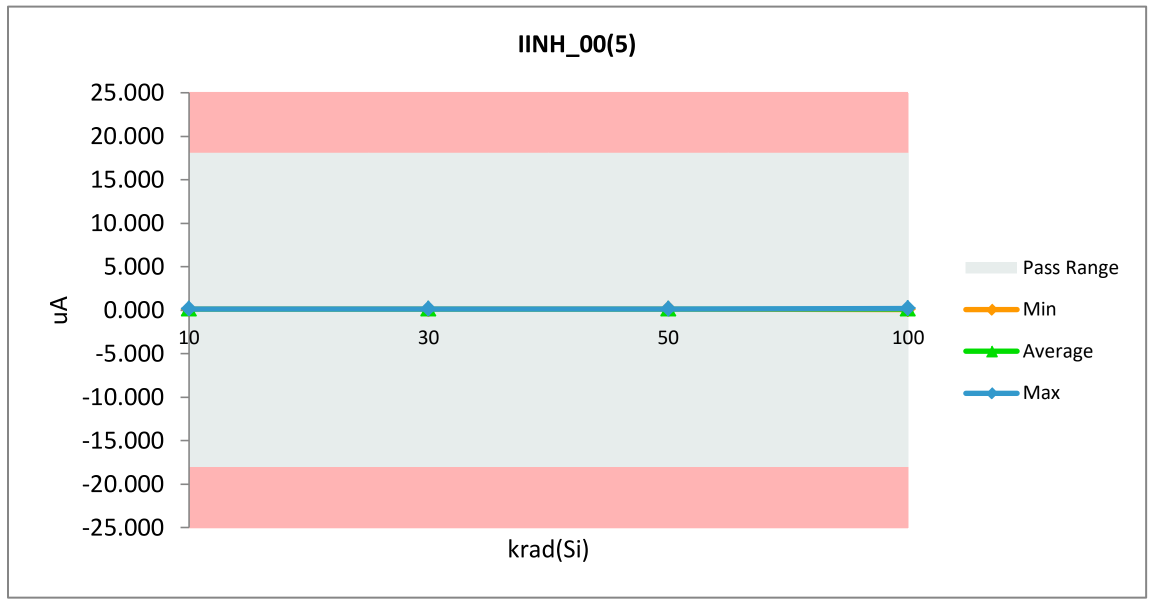


LDR Biased TID Report
SN55LVCP22A-SP

		IINH_00(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.143	0.149	-0.005
10	5	0.125	0.130	-0.005
10	7	0.125	0.149	-0.024
10	11	0.143	0.130	0.013
10	15	0.143	0.149	-0.005
10	20	0.143	0.149	-0.005
10	21	0.125	0.130	-0.005
10	24	0.125	0.130	-0.005
30	1	0.143	0.148	-0.005
30	5	0.125	0.129	-0.005
30	7	0.125	0.129	-0.005
30	11	0.143	0.148	-0.005
30	15	0.143	0.148	-0.005
30	20	0.143	0.129	0.014
30	21	0.125	0.148	-0.023
30	24	0.125	0.129	-0.005
50	1	0.143	0.158	-0.014
50	5	0.125	0.158	-0.033
50	7	0.125	0.139	-0.014
50	11	0.143	0.158	-0.014
50	15	0.143	0.158	-0.014
50	20	0.143	0.158	-0.014
50	21	0.125	0.158	-0.033
50	24	0.125	0.139	-0.014
100	3	0.143	0.175	-0.032
100	8	0.106	0.082	0.024
100	12	0.143	0.212	-0.069
100	13	0.125	0.082	0.043
100	16	0.125	0.212	-0.088
100	17	0.106	0.082	0.024
100	18	0.125	0.212	-0.088
100	19	0.143	0.175	-0.032
	Max	0.143	0.212	0.043
	Average	0.132	0.146	-0.014
	Min	0.106	0.082	-0.088
	Std Dev	0.011	0.031	0.028

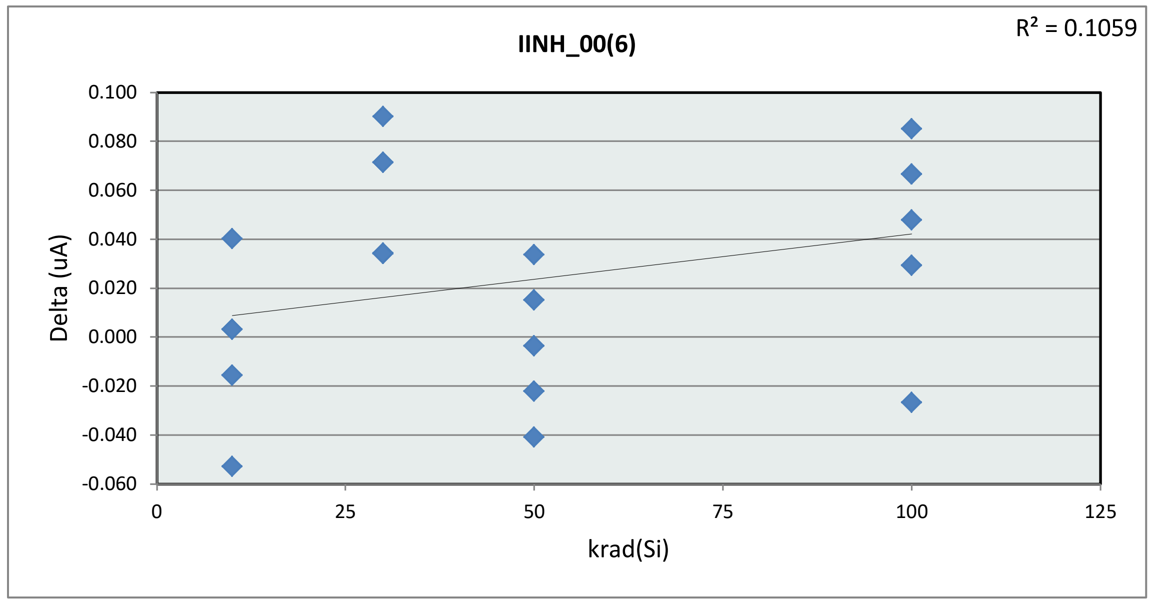


	IINH_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.130	0.129	0.139	0.082
Average	0.139	0.139	0.153	0.154
Max	0.149	0.148	0.158	0.212
UL	18.000	18.000	18.000	18.000

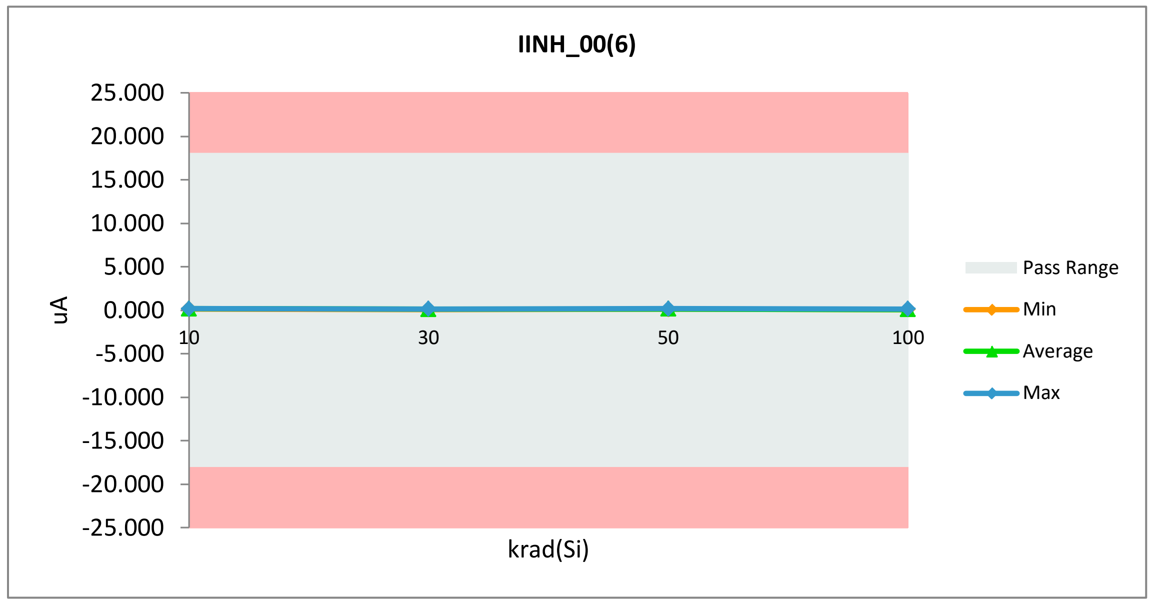


LDR Biased TID Report
SN55LVCP22A-SP

		IINH_00(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.145	0.198	-0.053
10	5	0.163	0.179	-0.016
10	7	0.126	0.142	-0.016
10	11	0.163	0.160	0.003
10	15	0.182	0.179	0.003
10	20	0.182	0.142	0.040
10	21	0.182	0.179	0.003
10	24	0.163	0.179	-0.016
30	1	0.145	0.111	0.034
30	5	0.163	0.092	0.071
30	7	0.126	0.092	0.034
30	11	0.163	0.129	0.034
30	15	0.182	0.111	0.071
30	20	0.182	0.148	0.034
30	21	0.182	0.092	0.090
30	24	0.163	0.092	0.071
50	1	0.145	0.167	-0.022
50	5	0.163	0.130	0.034
50	7	0.126	0.167	-0.041
50	11	0.163	0.167	-0.004
50	15	0.182	0.167	0.015
50	20	0.182	0.167	0.015
50	21	0.182	0.186	-0.004
50	24	0.163	0.186	-0.022
100	3	0.126	0.097	0.029
100	8	0.126	0.097	0.029
100	12	0.126	0.153	-0.027
100	13	0.182	0.097	0.085
100	16	0.163	0.097	0.067
100	17	0.145	0.078	0.067
100	18	0.163	0.116	0.048
100	19	0.182	0.116	0.067
	Max	0.182	0.198	0.090
	Average	0.161	0.138	0.023
	Min	0.126	0.078	-0.053
	Std Dev	0.021	0.037	0.039



	IINH_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.142	0.092	0.130	0.078
Average	0.170	0.108	0.167	0.106
Max	0.198	0.148	0.186	0.153
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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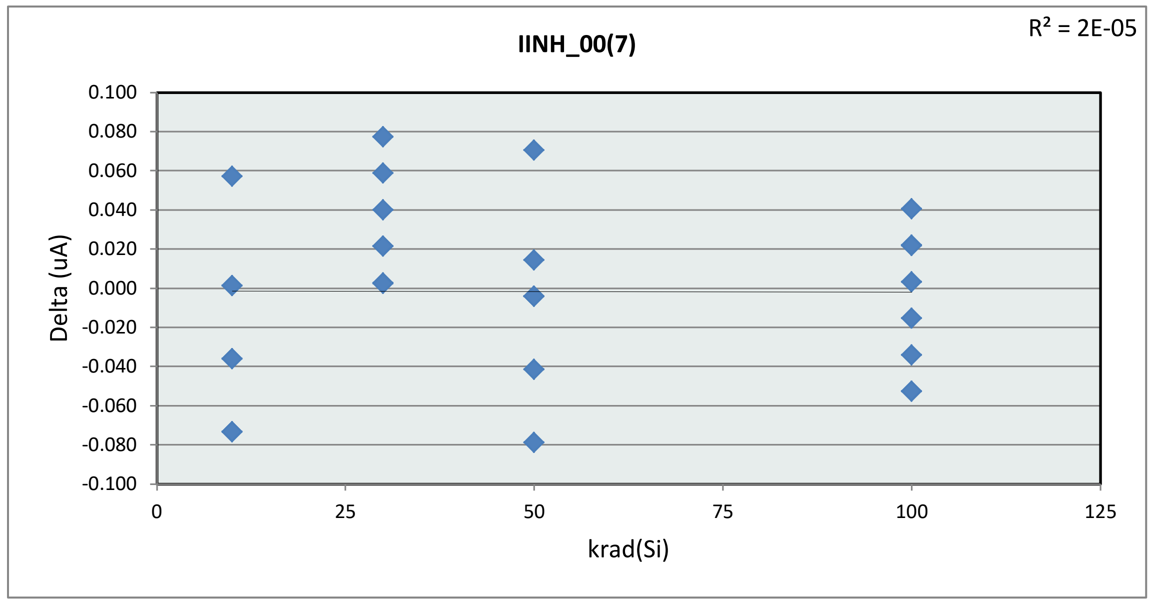
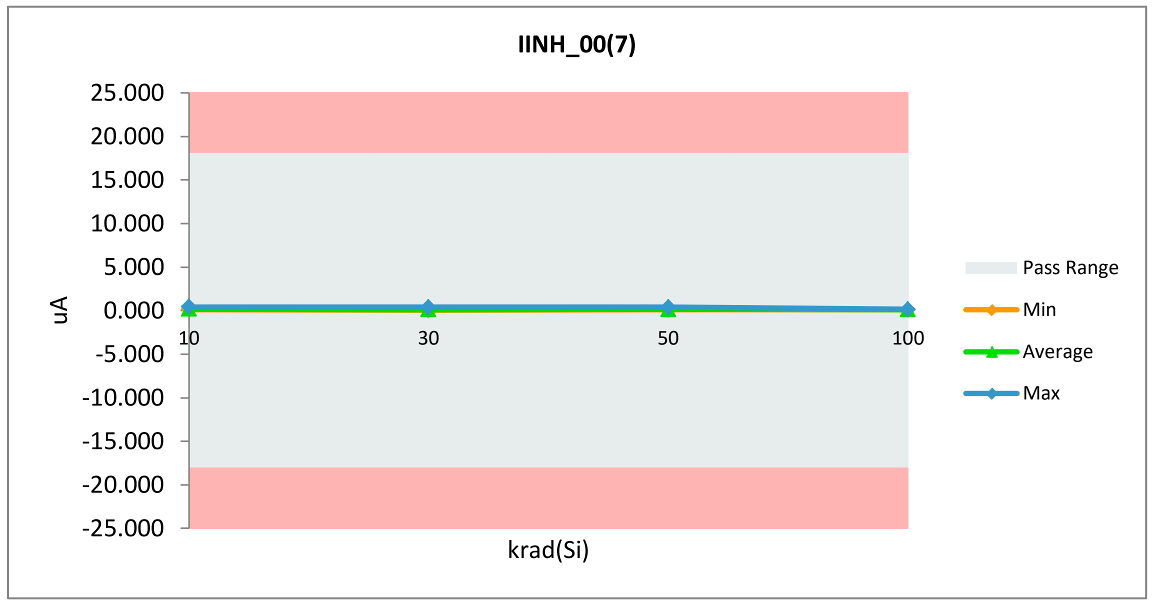
	IINH_00(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.101	0.174	-0.073
10	5	0.101	0.174	-0.073
10	7	0.101	0.137	-0.036
10	11	0.175	0.118	0.057
10	15	0.119	0.118	0.001
10	20	0.399	0.435	-0.036
10	21	0.138	0.137	0.001
10	24	0.082	0.155	-0.073
30	1	0.101	0.042	0.059
30	5	0.101	0.079	0.021
30	7	0.101	0.098	0.003
30	11	0.175	0.098	0.077
30	15	0.119	0.098	0.021
30	20	0.399	0.397	0.002
30	21	0.138	0.061	0.077
30	24	0.082	0.042	0.040
50	1	0.101	0.142	-0.041
50	5	0.101	0.105	-0.004
50	7	0.101	0.105	-0.004
50	11	0.175	0.105	0.070
50	15	0.119	0.124	-0.004
50	20	0.399	0.403	-0.004
50	21	0.138	0.124	0.014
50	24	0.082	0.161	-0.079
100	3	0.101	0.153	-0.053
100	8	0.157	0.116	0.040
100	12	0.175	0.153	0.022
100	13	0.101	0.116	-0.015
100	16	0.082	0.116	-0.034
100	17	0.101	0.098	0.003
100	18	0.101	0.153	-0.053
100	19	0.138	0.116	0.022
	Max	0.399	0.435	0.077
	Average	0.144	0.145	-0.002
	Min	0.082	0.042	-0.079
	Std Dev	0.088	0.093	0.045



	IINH_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.118	0.042	0.105	0.098
Average	0.181	0.114	0.159	0.128
Max	0.435	0.397	0.403	0.153
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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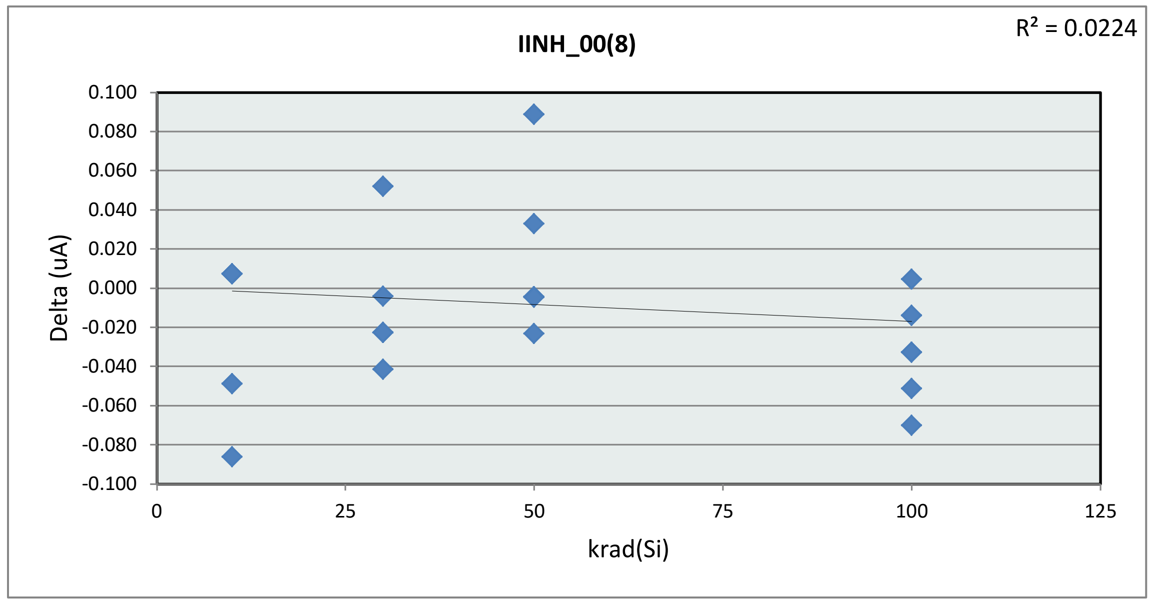
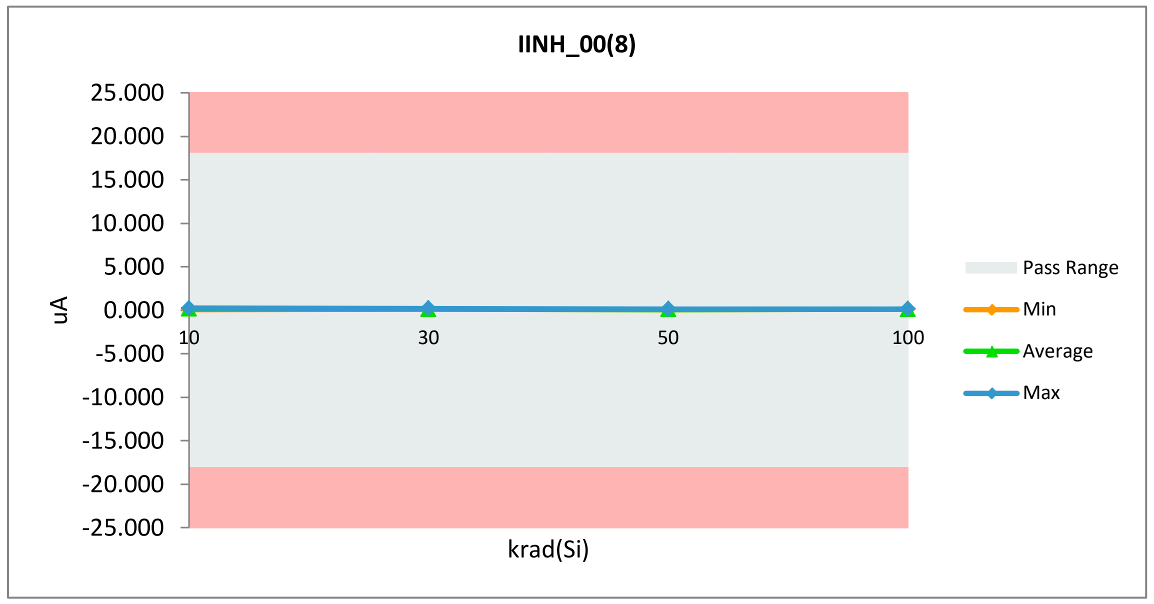
		IINH_00(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.108	0.157	-0.049
10	5	0.108	0.101	0.007
10	7	0.164	0.157	0.007
10	11	0.089	0.082	0.007
10	15	0.108	0.101	0.007
10	20	0.164	0.250	-0.086
10	21	0.164	0.157	0.007
10	24	0.089	0.138	-0.049
30	1	0.108	0.130	-0.023
30	5	0.108	0.112	-0.004
30	7	0.164	0.112	0.052
30	11	0.089	0.112	-0.023
30	15	0.108	0.130	-0.023
30	20	0.164	0.205	-0.041
30	21	0.164	0.112	0.052
30	24	0.089	0.112	-0.023
50	1	0.108	0.112	-0.005
50	5	0.108	0.112	-0.005
50	7	0.164	0.075	0.089
50	11	0.089	0.094	-0.005
50	15	0.108	0.131	-0.023
50	20	0.164	0.168	-0.005
50	21	0.164	0.075	0.089
50	24	0.089	0.056	0.033
100	3	0.108	0.122	-0.014
100	8	0.089	0.122	-0.033
100	12	0.108	0.140	-0.033
100	13	0.089	0.140	-0.051
100	16	0.089	0.122	-0.033
100	17	0.126	0.122	0.005
100	18	0.070	0.140	-0.070
100	19	0.126	0.140	-0.014
	Max	0.164	0.250	0.089
	Average	0.118	0.126	-0.008
	Min	0.070	0.056	-0.086
	Std Dev	0.031	0.037	0.039

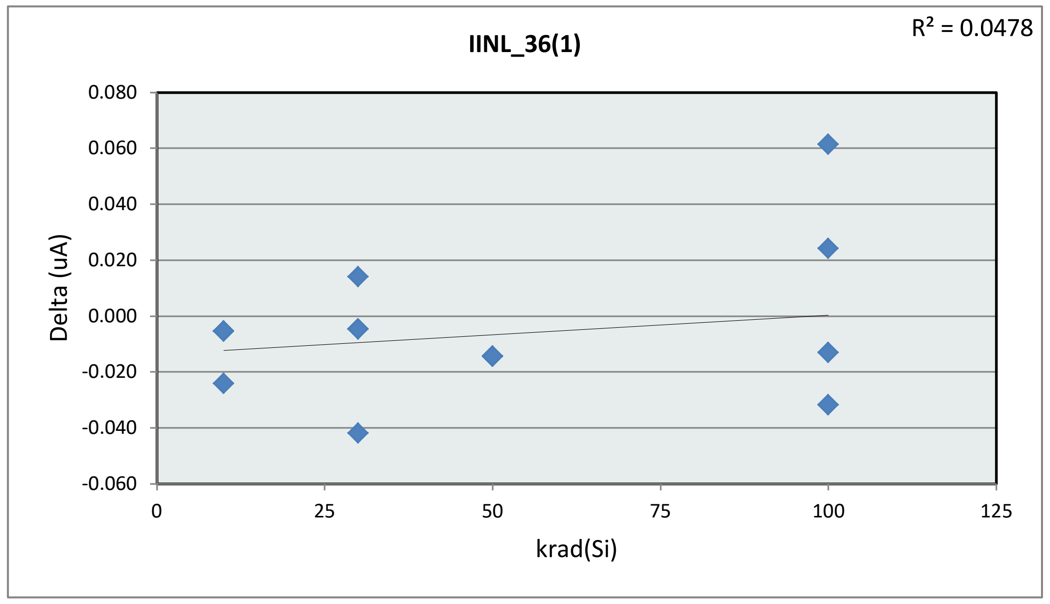


	IINH_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.082	0.112	0.056	0.122
Average	0.143	0.128	0.103	0.131
Max	0.250	0.205	0.168	0.140
UL	18.000	18.000	18.000	18.000

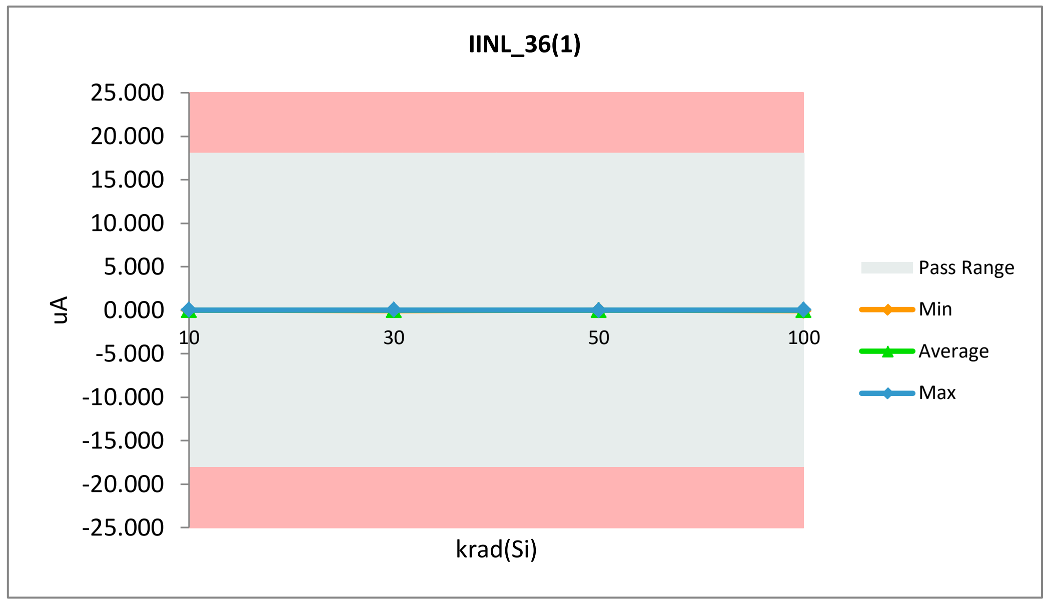


LDR Biased TID Report
SN55LVCP22A-SP

		IINL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.006	0.000	-0.005
10	5	-0.006	0.000	-0.005
10	7	-0.006	0.000	-0.005
10	11	-0.006	0.018	-0.024
10	15	-0.006	0.000	-0.005
10	20	-0.006	0.000	-0.005
10	21	-0.006	0.000	-0.005
10	24	-0.006	0.018	-0.024
30	1	-0.006	-0.001	-0.005
30	5	-0.006	-0.001	-0.005
30	7	-0.006	-0.001	-0.005
30	11	-0.006	0.036	-0.042
30	15	-0.006	-0.001	-0.005
30	20	-0.006	-0.020	0.014
30	21	-0.006	-0.001	-0.005
30	24	-0.006	-0.001	-0.005
50	1	-0.006	0.009	-0.014
50	5	-0.006	0.009	-0.014
50	7	-0.006	0.009	-0.014
50	11	-0.006	0.009	-0.014
50	15	-0.006	0.009	-0.014
50	20	-0.006	0.009	-0.014
50	21	-0.006	0.009	-0.014
50	24	-0.006	0.009	-0.014
100	3	-0.006	0.026	-0.032
100	8	-0.006	-0.067	0.061
100	12	-0.006	0.026	-0.032
100	13	-0.006	0.007	-0.013
100	16	-0.006	0.026	-0.032
100	17	-0.006	-0.030	0.024
100	18	0.013	0.026	-0.013
100	19	-0.006	-0.067	0.061
	Max	0.013	0.036	0.061
	Average	-0.005	0.002	-0.007
	Min	-0.006	-0.067	-0.042
	Std Dev	0.003	0.022	0.022

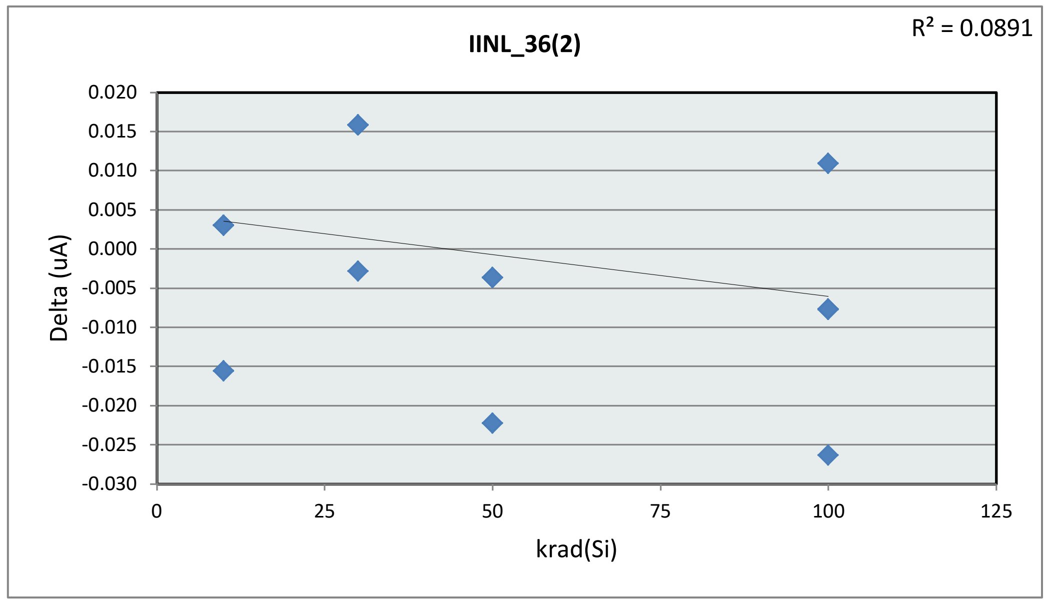


	IINL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.000	-0.020	0.009	-0.067
Average	0.004	0.001	0.009	-0.007
Max	0.018	0.036	0.009	0.026
UL	18.000	18.000	18.000	18.000

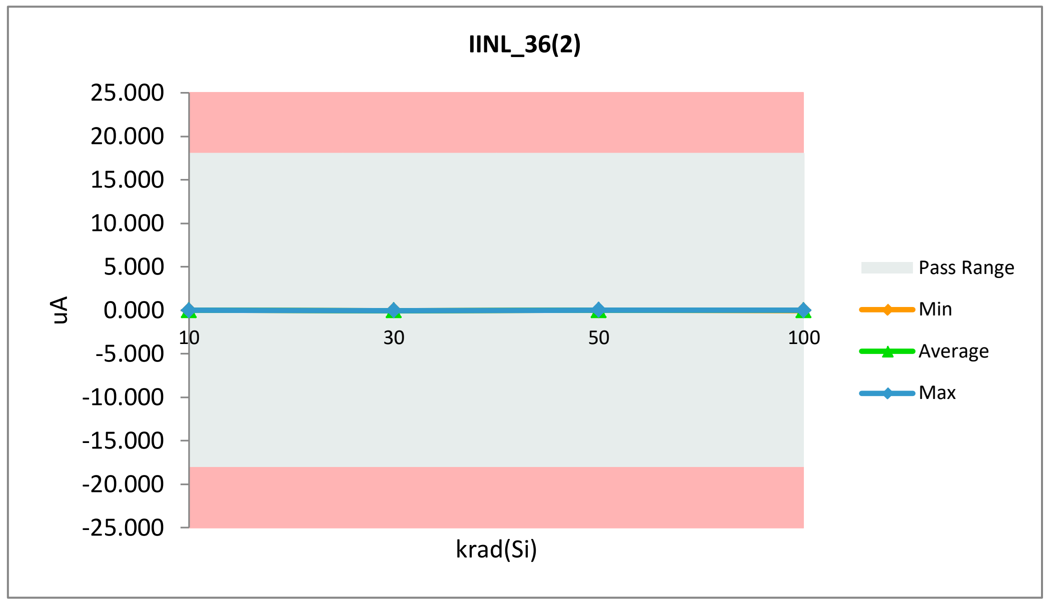


LDR Biased TID Report
SN55LVCP22A-SP

		IINL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.004	-0.007	0.003
10	5	-0.004	-0.007	0.003
10	7	-0.004	-0.007	0.003
10	11	-0.004	-0.007	0.003
10	15	-0.004	-0.007	0.003
10	20	-0.004	0.011	-0.016
10	21	-0.023	-0.007	-0.016
10	24	-0.004	-0.007	0.003
30	1	-0.004	-0.020	0.016
30	5	-0.004	-0.020	0.016
30	7	-0.004	-0.020	0.016
30	11	-0.004	-0.020	0.016
30	15	-0.004	-0.020	0.016
30	20	-0.004	-0.020	0.016
30	21	-0.023	-0.020	-0.003
30	24	-0.004	-0.020	0.016
50	1	-0.004	0.000	-0.004
50	5	-0.004	0.000	-0.004
50	7	-0.004	0.000	-0.004
50	11	-0.004	0.000	-0.004
50	15	-0.004	0.018	-0.022
50	20	-0.004	0.000	-0.004
50	21	-0.023	0.000	-0.022
50	24	-0.004	0.000	-0.004
100	3	-0.004	0.004	-0.008
100	8	-0.004	-0.015	0.011
100	12	-0.004	0.004	-0.008
100	13	-0.023	-0.015	-0.008
100	16	-0.004	-0.015	0.011
100	17	-0.023	-0.015	-0.008
100	18	-0.023	-0.015	-0.008
100	19	-0.023	0.004	-0.026
	Max	-0.004	0.018	0.016
	Average	-0.008	-0.008	0.000
	Min	-0.023	-0.020	-0.026
	Std Dev	0.008	0.010	0.012

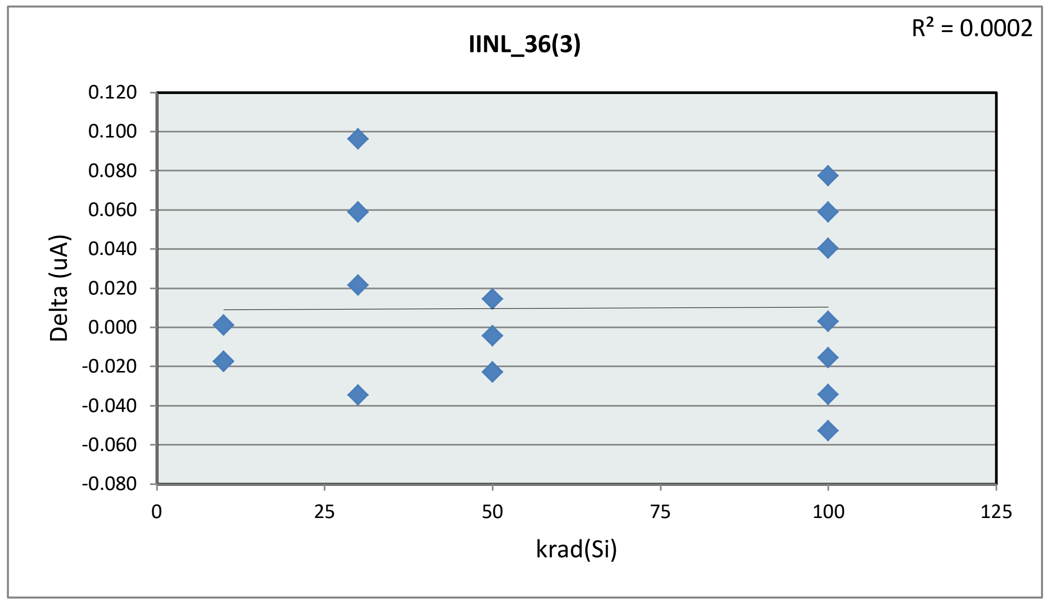


	IINL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.007	-0.020	0.000	-0.015
Average	-0.005	-0.020	0.002	-0.008
Max	0.011	-0.020	0.018	0.004
UL	18.000	18.000	18.000	18.000

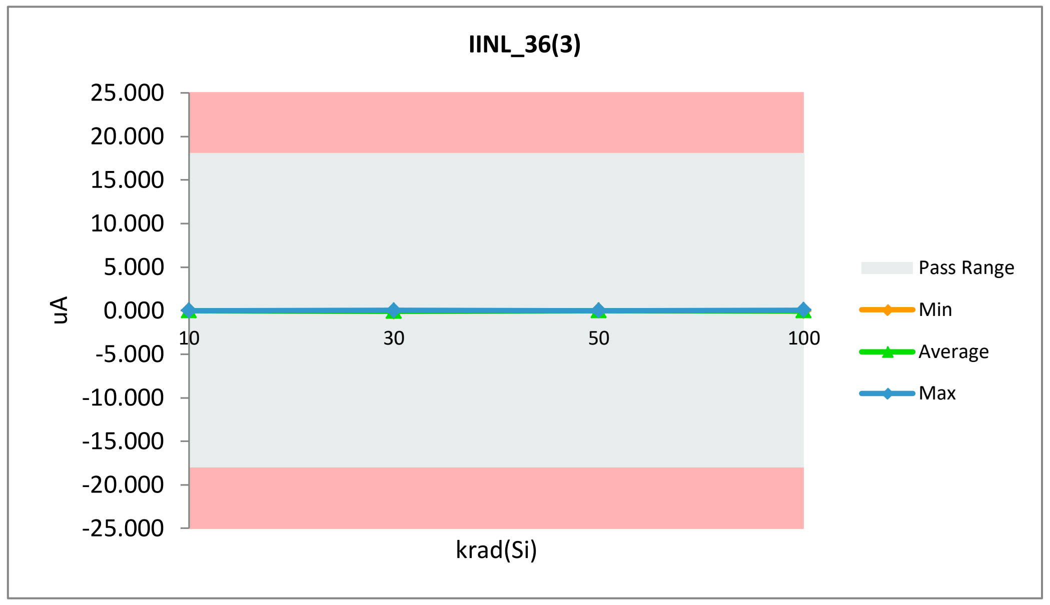


LDR Biased TID Report
SN55LVCP22A-SP

		IINL_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.011	0.006	-0.017
10	5	-0.011	0.006	-0.017
10	7	0.008	0.006	0.001
10	11	-0.011	0.006	-0.017
10	15	-0.011	0.006	-0.017
10	20	0.008	0.006	0.001
10	21	-0.011	0.006	-0.017
10	24	0.008	0.006	0.001
30	1	-0.011	-0.070	0.059
30	5	-0.011	0.023	-0.034
30	7	0.008	-0.089	0.096
30	11	-0.011	-0.070	0.059
30	15	-0.011	-0.033	0.021
30	20	0.008	-0.089	0.096
30	21	-0.011	-0.070	0.059
30	24	0.008	-0.014	0.021
50	1	-0.011	0.012	-0.023
50	5	-0.011	0.012	-0.023
50	7	0.008	-0.007	0.014
50	11	-0.011	0.012	-0.023
50	15	-0.011	0.012	-0.023
50	20	0.008	-0.007	0.014
50	21	-0.011	-0.007	-0.004
50	24	0.008	0.012	-0.004
100	3	0.008	0.004	0.003
100	8	0.008	-0.051	0.059
100	12	-0.011	-0.051	0.040
100	13	-0.011	0.023	-0.034
100	16	0.008	0.023	-0.016
100	17	0.008	0.060	-0.053
100	18	-0.011	-0.014	0.003
100	19	0.008	-0.070	0.078
	Max	0.008	0.060	0.096
	Average	-0.003	-0.012	0.009
	Min	-0.011	-0.089	-0.053
	Std Dev	0.009	0.037	0.039



	IINL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.006	-0.089	-0.007	-0.070
Average	0.006	-0.051	0.005	-0.009
Max	0.006	0.023	0.012	0.060
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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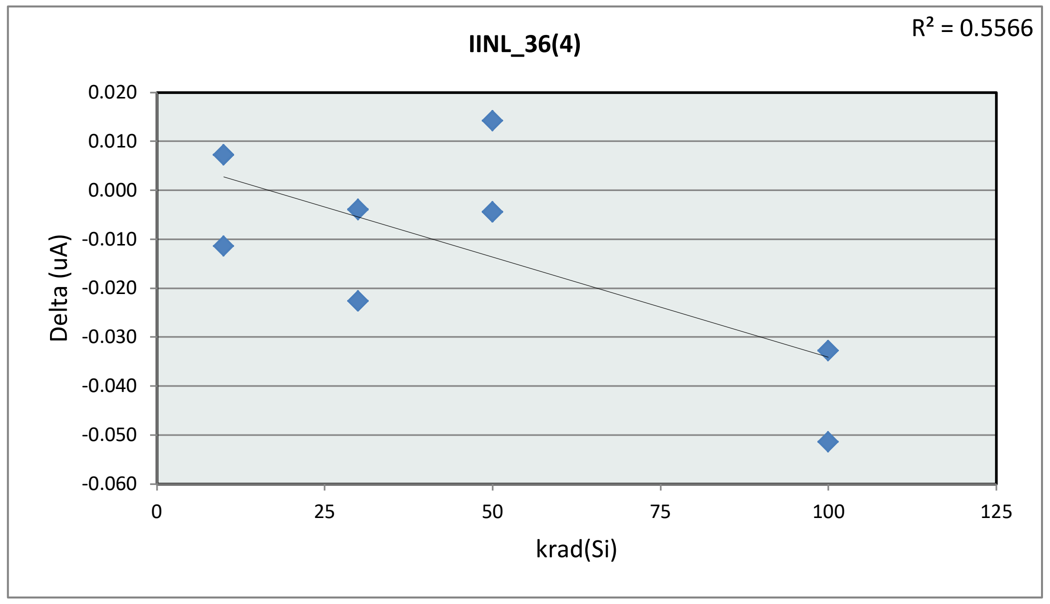
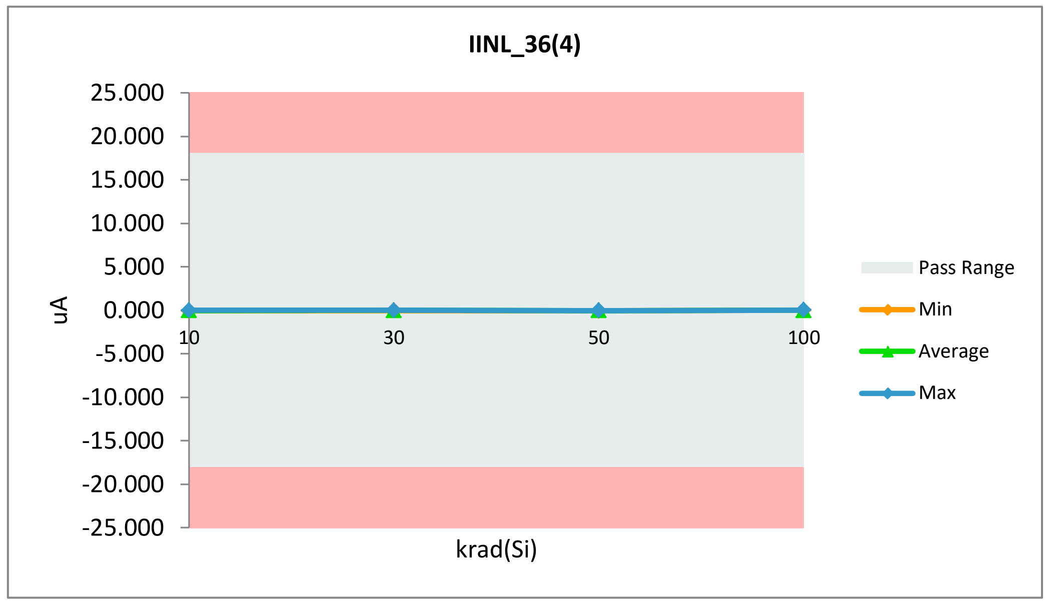
	IINL_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.023	-0.011	-0.011
10	5	-0.023	-0.030	0.007
10	7	-0.023	-0.030	0.007
10	11	-0.023	-0.030	0.007
10	15	-0.023	-0.030	0.007
10	20	-0.041	-0.049	0.007
10	21	-0.023	-0.030	0.007
10	24	-0.023	-0.030	0.007
30	1	-0.023	0.000	-0.023
30	5	-0.023	-0.019	-0.004
30	7	-0.023	0.000	-0.023
30	11	-0.023	0.000	-0.023
30	15	-0.023	0.000	-0.023
30	20	-0.041	-0.037	-0.004
30	21	-0.023	0.000	-0.023
30	24	-0.023	0.000	-0.023
50	1	-0.023	-0.037	0.014
50	5	-0.023	-0.018	-0.004
50	7	-0.023	-0.018	-0.004
50	11	-0.023	-0.018	-0.004
50	15	-0.023	-0.018	-0.004
50	20	-0.041	-0.056	0.014
50	21	-0.023	-0.018	-0.004
50	24	-0.023	-0.018	-0.004
100	3	-0.023	0.029	-0.051
100	8	-0.023	0.029	-0.051
100	12	-0.023	0.010	-0.033
100	13	-0.023	0.010	-0.033
100	16	-0.023	0.010	-0.033
100	17	-0.023	0.010	-0.033
100	18	-0.023	0.010	-0.033
100	19	-0.023	0.010	-0.033
	Max	-0.023	0.029	0.014
	Average	-0.025	-0.012	-0.013
	Min	-0.041	-0.056	-0.051
	Std Dev	0.006	0.021	0.019



	IINL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.049	-0.037	-0.056	0.010
Average	-0.030	-0.007	-0.025	0.015
Max	-0.011	0.000	-0.018	0.029
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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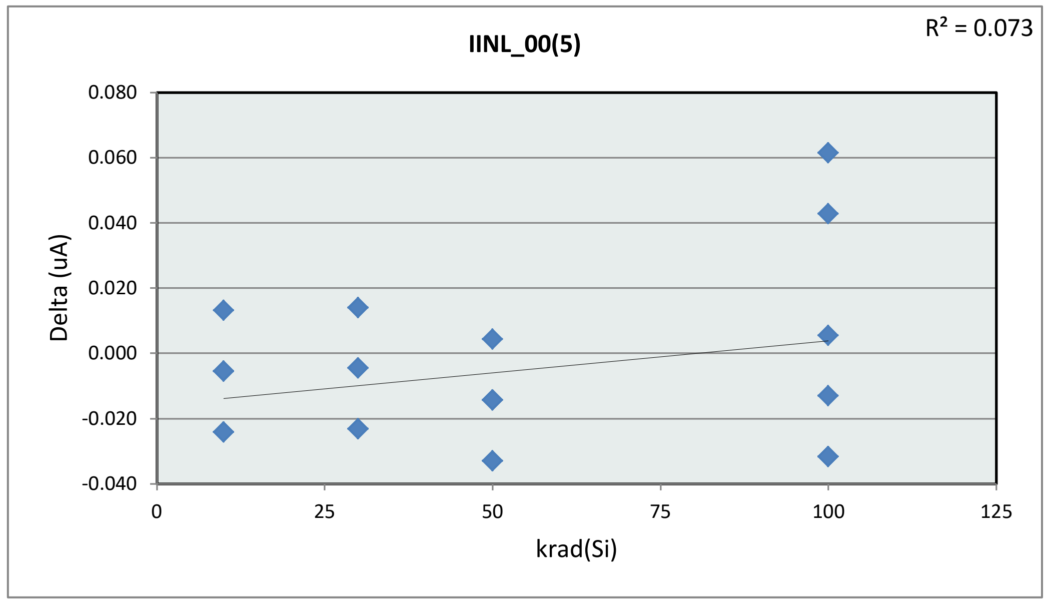
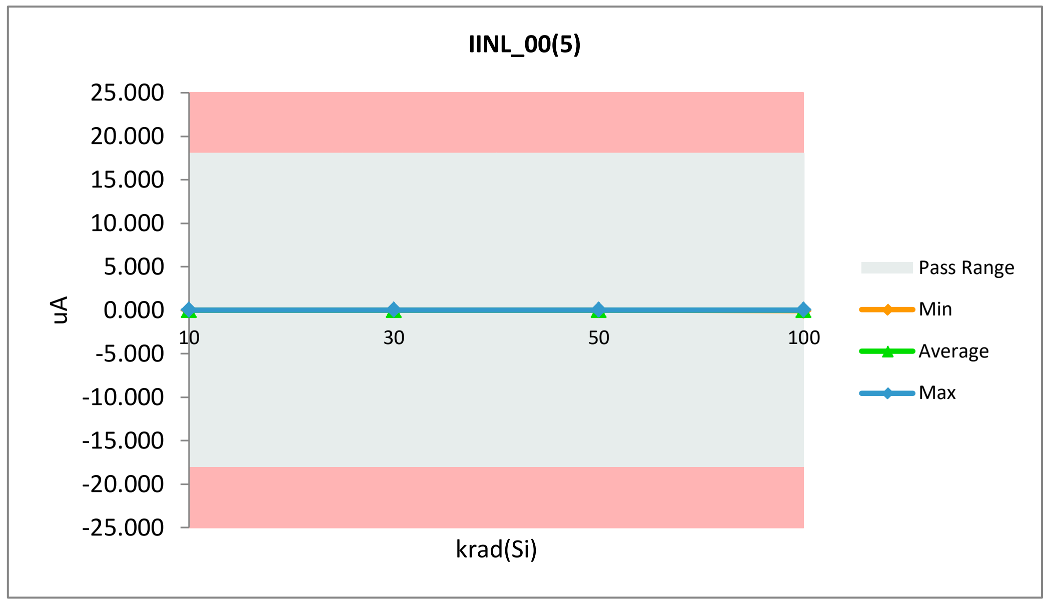
		IINL_00(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.006	0.000	-0.005
10	5	-0.006	0.018	-0.024
10	7	-0.006	0.000	-0.005
10	11	0.013	0.000	0.013
10	15	-0.006	0.018	-0.024
10	20	-0.006	0.018	-0.024
10	21	-0.006	0.000	-0.005
10	24	0.013	0.018	-0.005
30	1	-0.006	-0.001	-0.005
30	5	-0.006	-0.001	-0.005
30	7	-0.006	0.017	-0.023
30	11	0.013	-0.001	0.014
30	15	-0.006	0.017	-0.023
30	20	-0.006	0.017	-0.023
30	21	-0.006	-0.001	-0.005
30	24	0.013	-0.001	0.014
50	1	-0.006	0.009	-0.014
50	5	-0.006	0.009	-0.014
50	7	-0.006	0.009	-0.014
50	11	0.013	0.027	-0.014
50	15	-0.006	0.009	-0.014
50	20	-0.006	0.027	-0.033
50	21	-0.006	0.027	-0.033
50	24	0.013	0.009	0.004
100	3	-0.006	-0.011	0.006
100	8	0.013	-0.030	0.043
100	12	-0.006	0.026	-0.032
100	13	-0.006	0.007	-0.013
100	16	-0.006	-0.067	0.061
100	17	-0.006	0.026	-0.032
100	18	-0.006	0.026	-0.032
100	19	-0.006	-0.067	0.061
	Max	0.013	0.027	0.061
	Average	-0.002	0.005	-0.006
	Min	-0.006	-0.067	-0.033
	Std Dev	0.008	0.023	0.025



	IINL_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.000	-0.001	0.009	-0.067
Average	0.009	0.006	0.016	-0.011
Max	0.018	0.017	0.027	0.026
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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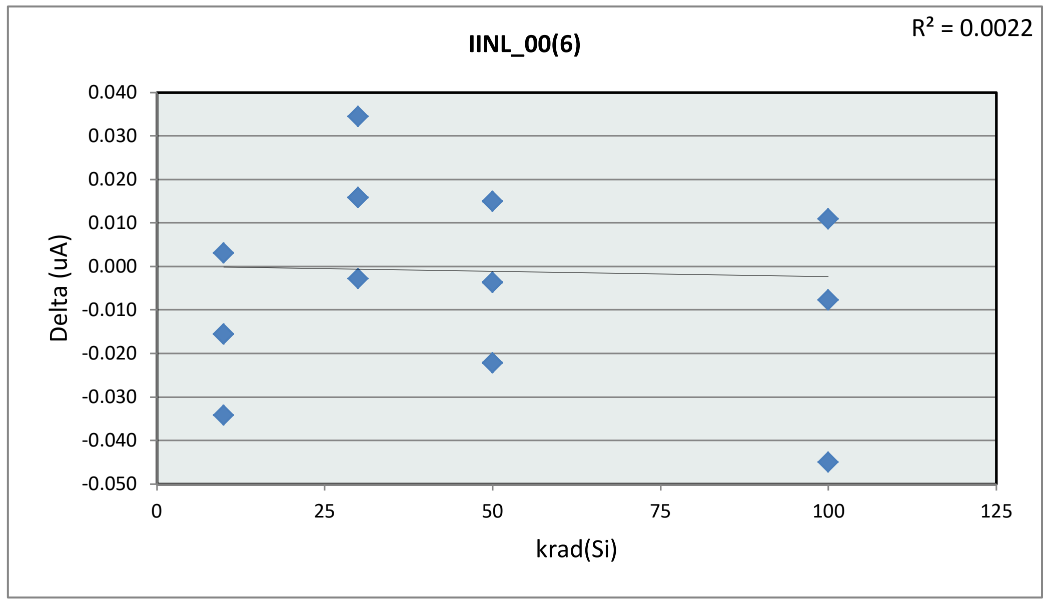
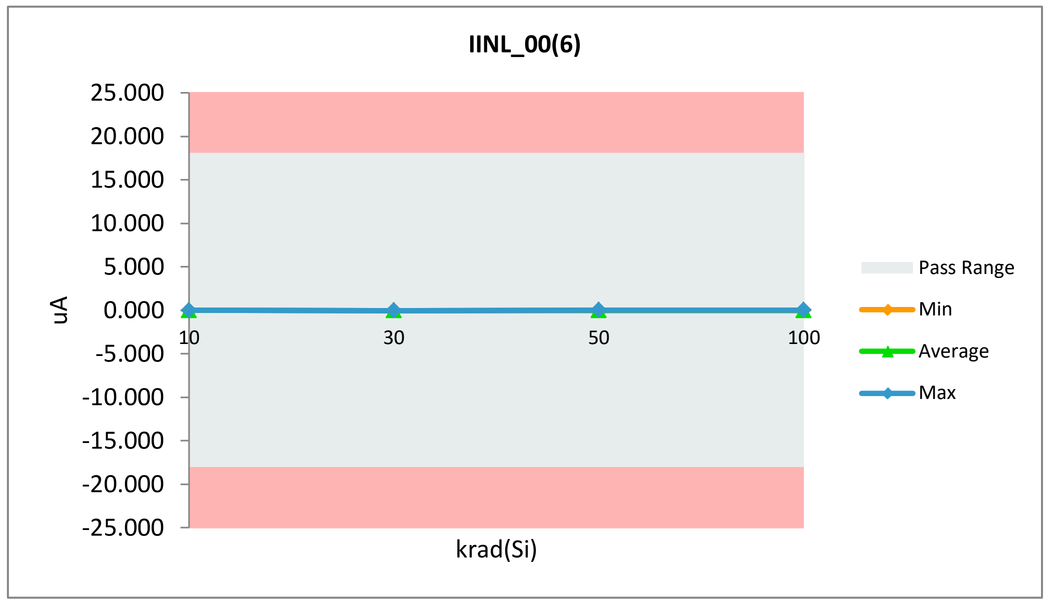
	IINL_00(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.023	0.011	-0.034
10	5	-0.004	-0.007	0.003
10	7	-0.004	0.011	-0.016
10	11	-0.004	0.011	-0.016
10	15	0.014	0.011	0.003
10	20	-0.004	0.011	-0.016
10	21	-0.004	0.011	-0.016
10	24	-0.004	0.011	-0.016
30	1	-0.023	-0.020	-0.003
30	5	-0.004	-0.020	0.016
30	7	-0.004	-0.020	0.016
30	11	-0.004	-0.020	0.016
30	15	0.014	-0.020	0.034
30	20	-0.004	-0.020	0.016
30	21	-0.004	-0.039	0.034
30	24	-0.004	-0.020	0.016
50	1	-0.023	0.000	-0.022
50	5	-0.004	0.018	-0.022
50	7	-0.004	0.000	-0.004
50	11	-0.004	0.000	-0.004
50	15	0.014	0.000	0.015
50	20	-0.004	0.000	-0.004
50	21	-0.004	0.000	-0.004
50	24	-0.004	-0.019	0.015
100	3	-0.023	-0.015	-0.008
100	8	-0.023	-0.015	-0.008
100	12	-0.004	0.041	-0.045
100	13	-0.023	-0.015	-0.008
100	16	-0.004	-0.015	0.011
100	17	0.014	0.004	0.011
100	18	-0.023	-0.015	-0.008
100	19	-0.004	-0.015	0.011
	Max	0.014	0.041	0.034
	Average	-0.006	-0.005	-0.001
	Min	-0.023	-0.039	-0.045
	Std Dev	0.011	0.016	0.018



	IINL_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.007	-0.039	-0.019	-0.015
Average	0.009	-0.022	0.000	-0.006
Max	0.011	-0.020	0.018	0.041
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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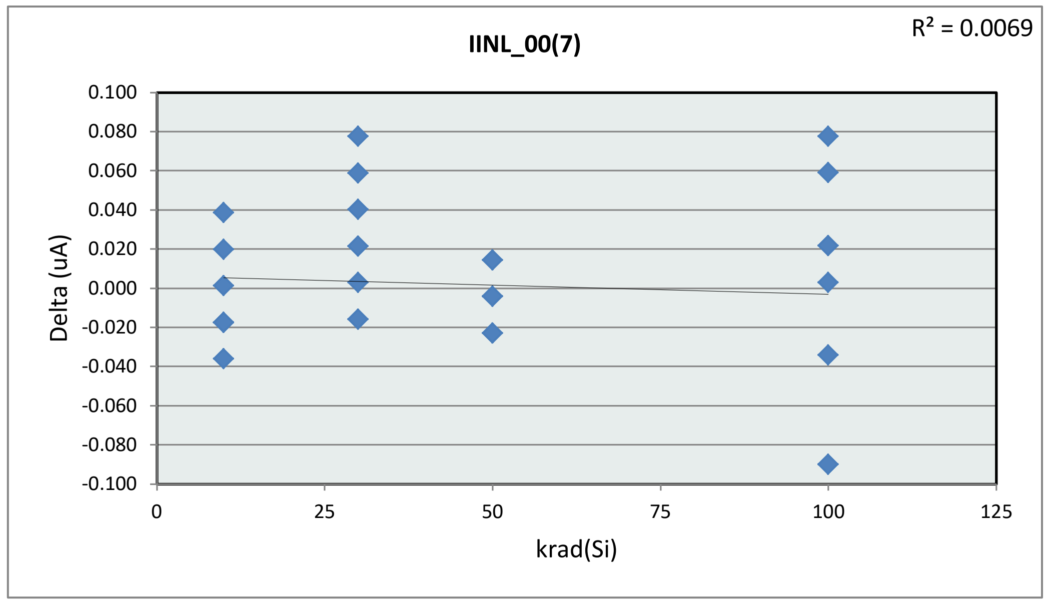
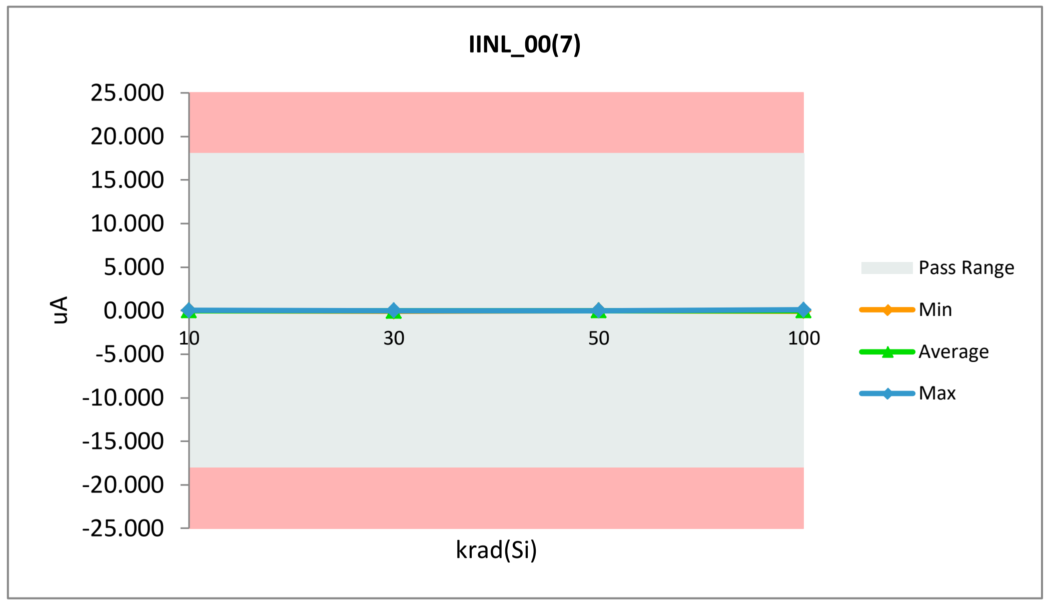
		IINL_00(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.008	-0.012	0.020
10	5	-0.030	-0.012	-0.017
10	7	-0.011	0.025	-0.036
10	11	0.026	-0.012	0.038
10	15	-0.011	0.006	-0.017
10	20	-0.011	-0.012	0.001
10	21	-0.030	-0.012	-0.017
10	24	-0.011	0.006	-0.017
30	1	0.008	-0.014	0.021
30	5	-0.030	-0.014	-0.016
30	7	-0.011	-0.089	0.077
30	11	0.026	-0.014	0.040
30	15	-0.011	-0.070	0.059
30	20	-0.011	-0.033	0.021
30	21	-0.030	-0.014	-0.016
30	24	-0.011	-0.014	0.003
50	1	0.008	-0.007	0.014
50	5	-0.030	-0.007	-0.023
50	7	-0.011	-0.007	-0.004
50	11	0.026	0.012	0.014
50	15	-0.011	0.012	-0.023
50	20	-0.011	-0.007	-0.004
50	21	-0.030	-0.007	-0.023
50	24	-0.011	-0.007	-0.004
100	3	-0.011	0.079	-0.090
100	8	-0.011	0.079	-0.090
100	12	0.008	-0.070	0.078
100	13	-0.011	0.023	-0.034
100	16	-0.011	-0.033	0.022
100	17	0.008	-0.051	0.059
100	18	-0.011	-0.014	0.003
100	19	0.008	-0.014	0.022
	Max	0.026	0.079	0.078
	Average	-0.008	-0.009	0.002
	Min	-0.030	-0.089	-0.090
	Std Dev	0.016	0.034	0.039



	IINL_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.012	-0.089	-0.007	-0.070
Average	-0.003	-0.033	-0.002	0.000
Max	0.025	-0.014	0.012	0.079
UL	18.000	18.000	18.000	18.000



LDR Biased TID Report
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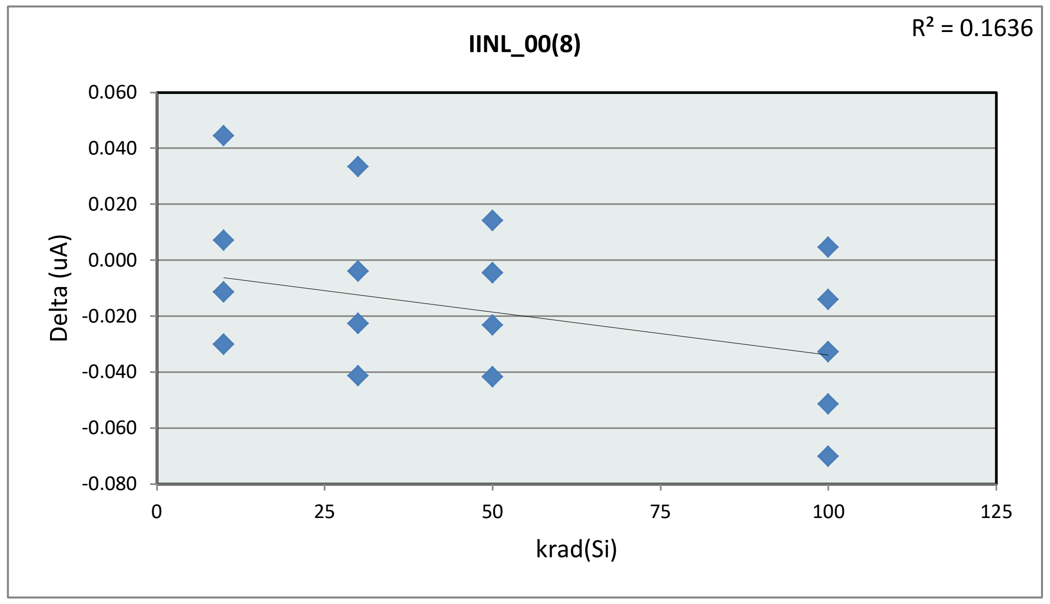
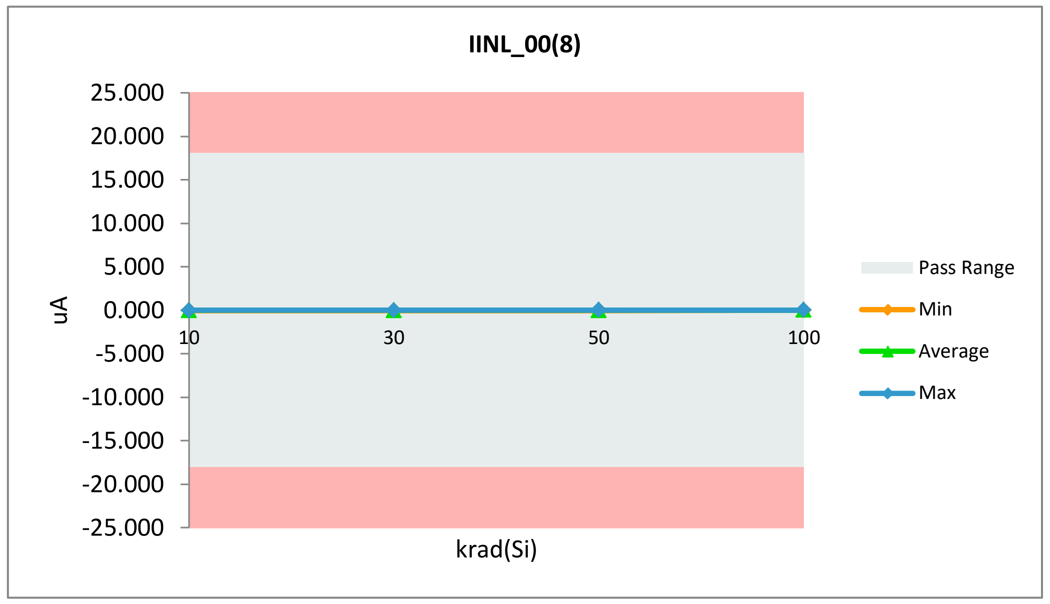
		IINL_00(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		18	18	
Min Limit		-18	-18	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.041	-0.030	-0.011
10	5	-0.023	0.007	-0.030
10	7	0.014	-0.030	0.044
10	11	-0.041	-0.011	-0.030
10	15	-0.023	-0.011	-0.011
10	20	-0.023	-0.030	0.007
10	21	-0.023	0.007	-0.030
10	24	-0.041	-0.011	-0.030
30	1	-0.041	-0.019	-0.023
30	5	-0.023	0.000	-0.023
30	7	0.014	-0.019	0.033
30	11	-0.041	-0.019	-0.023
30	15	-0.023	-0.019	-0.004
30	20	-0.023	-0.019	-0.004
30	21	-0.023	-0.019	-0.004
30	24	-0.041	0.000	-0.041
50	1	-0.041	-0.037	-0.004
50	5	-0.023	-0.037	0.014
50	7	0.014	0.019	-0.005
50	11	-0.041	-0.037	-0.004
50	15	-0.023	-0.037	0.014
50	20	-0.023	0.019	-0.042
50	21	-0.023	0.019	-0.042
50	24	-0.041	-0.018	-0.023
100	3	-0.004	0.029	-0.033
100	8	0.014	0.010	0.005
100	12	-0.041	0.029	-0.070
100	13	-0.023	0.010	-0.033
100	16	0.014	0.029	-0.014
100	17	-0.041	0.010	-0.051
100	18	-0.023	0.010	-0.033
100	19	-0.041	0.029	-0.070
	Max	0.014	0.029	0.044
	Average	-0.023	-0.006	-0.018
	Min	-0.041	-0.037	-0.070
	Std Dev	0.019	0.022	0.026

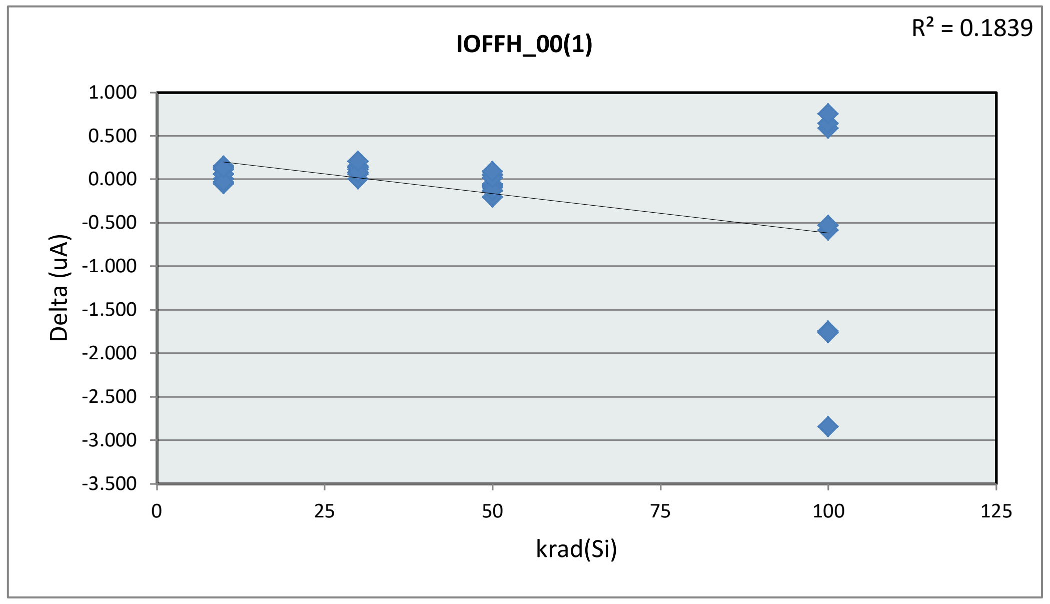


	IINL_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.030	-0.019	-0.037	0.010
Average	-0.014	-0.014	-0.014	0.019
Max	0.007	0.000	0.019	0.029
UL	18.000	18.000	18.000	18.000

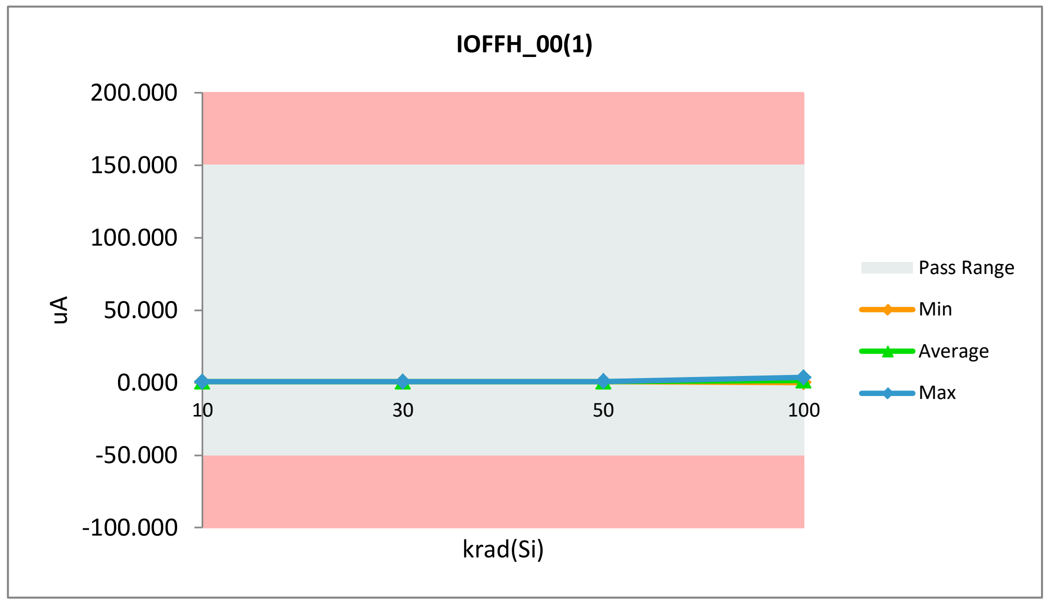


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.747	0.632	0.116
10	5	0.673	0.725	-0.052
10	7	0.766	0.613	0.153
10	11	0.822	0.762	0.060
10	15	0.692	0.687	0.004
10	20	0.729	0.669	0.060
10	21	0.692	0.725	-0.033
10	24	0.822	0.687	0.134
30	1	0.747	0.614	0.134
30	5	0.673	0.614	0.059
30	7	0.766	0.614	0.152
30	11	0.822	0.614	0.208
30	15	0.692	0.688	0.004
30	20	0.729	0.614	0.115
30	21	0.692	0.614	0.078
30	24	0.822	0.614	0.208
50	1	0.747	0.824	-0.076
50	5	0.673	0.880	-0.207
50	7	0.766	0.712	0.054
50	11	0.822	0.880	-0.058
50	15	0.692	0.787	-0.095
50	20	0.729	0.861	-0.132
50	21	0.692	0.675	0.017
50	24	0.822	0.731	0.091
100	3	0.710	2.454	-1.744
100	8	0.803	3.646	-2.843
100	12	0.654	0.071	0.584
100	13	0.673	1.262	-0.589
100	16	0.692	2.454	-1.762
100	17	0.710	0.071	0.640
100	18	0.729	1.262	-0.533
100	19	0.822	0.071	0.751
	Max	0.822	3.646	0.751
	Average	0.738	0.879	-0.141
	Min	0.654	0.071	-2.843
	Std Dev	0.056	0.714	0.715

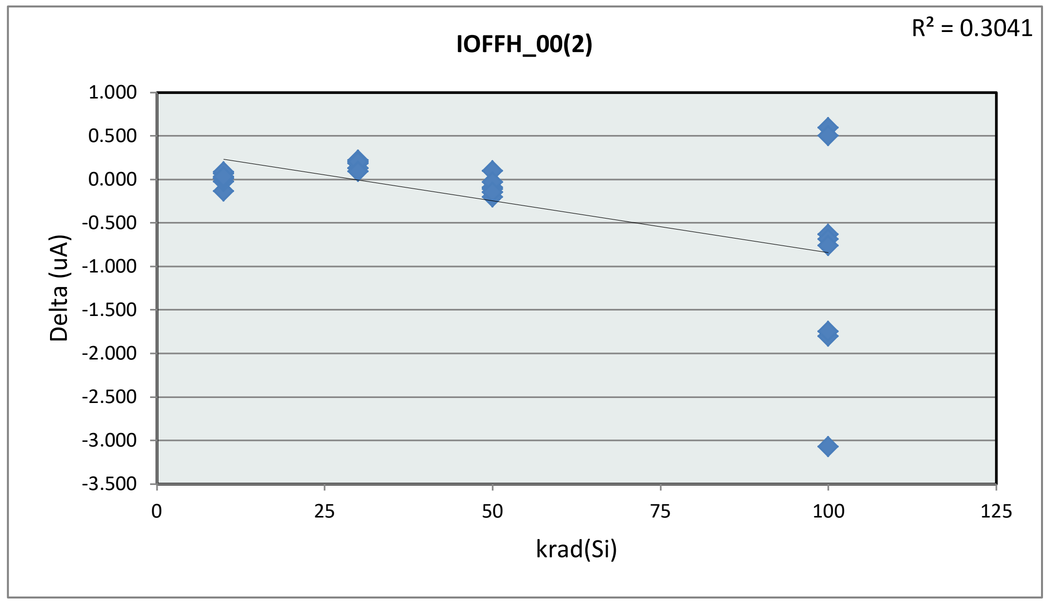


	IOFFH_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.613	0.614	0.675	0.071
Average	0.687	0.623	0.794	1.411
Max	0.762	0.688	0.880	3.646
UL	150.000	150.000	150.000	150.000

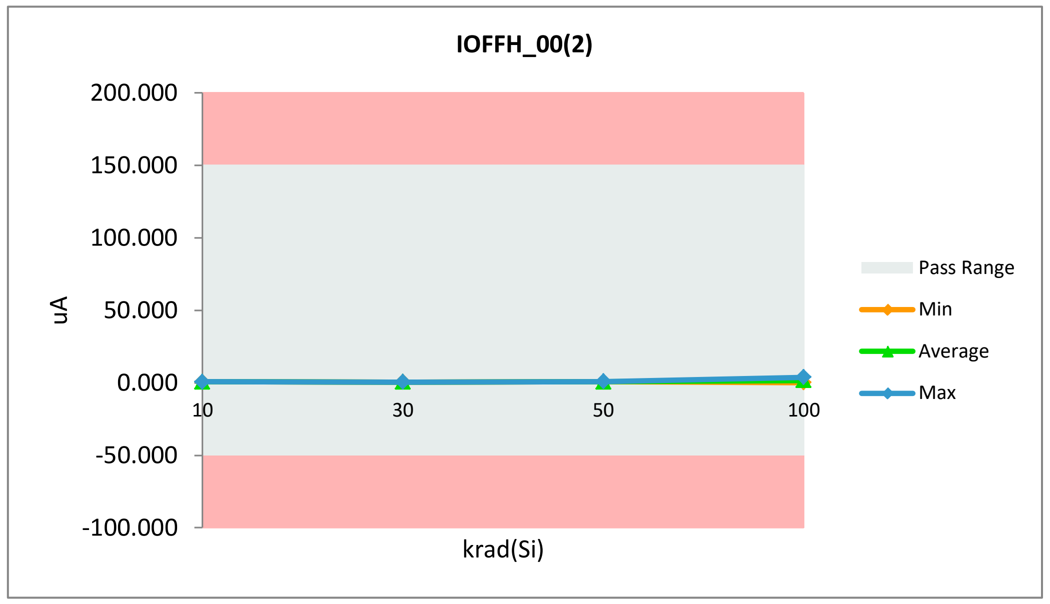


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.627	0.765	-0.137
10	5	0.758	0.746	0.012
10	7	0.627	0.616	0.012
10	11	0.795	0.727	0.068
10	15	0.776	0.690	0.086
10	20	0.627	0.653	-0.025
10	21	0.702	0.690	0.012
10	24	0.665	0.634	0.030
30	1	0.627	0.503	0.125
30	5	0.758	0.577	0.180
30	7	0.627	0.503	0.125
30	11	0.795	0.577	0.218
30	15	0.776	0.577	0.199
30	20	0.627	0.503	0.125
30	21	0.702	0.503	0.199
30	24	0.665	0.577	0.087
50	1	0.627	0.719	-0.091
50	5	0.758	0.868	-0.110
50	7	0.627	0.775	-0.147
50	11	0.795	0.830	-0.035
50	15	0.776	0.681	0.095
50	20	0.627	0.830	-0.203
50	21	0.702	0.737	-0.035
50	24	0.665	0.812	-0.147
100	3	0.758	2.564	-1.806
100	8	0.683	3.755	-3.072
100	12	0.776	0.182	0.594
100	13	0.739	1.373	-0.634
100	16	0.814	2.564	-1.750
100	17	0.683	1.373	-0.690
100	18	0.609	1.373	-0.764
100	19	0.683	0.182	0.501
	Max	0.814	3.755	0.594
	Average	0.702	0.921	-0.218
	Min	0.609	0.182	-3.072
	Std Dev	0.067	0.739	0.733

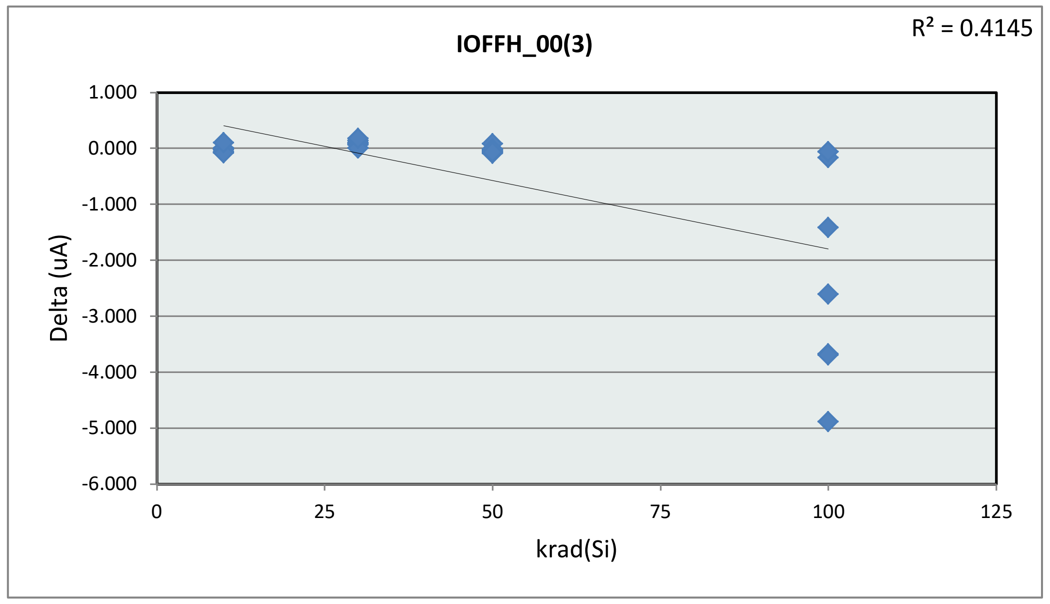


	IOFFH_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.616	0.503	0.681	0.182
Average	0.690	0.540	0.782	1.671
Max	0.765	0.577	0.868	3.755
UL	150.000	150.000	150.000	150.000

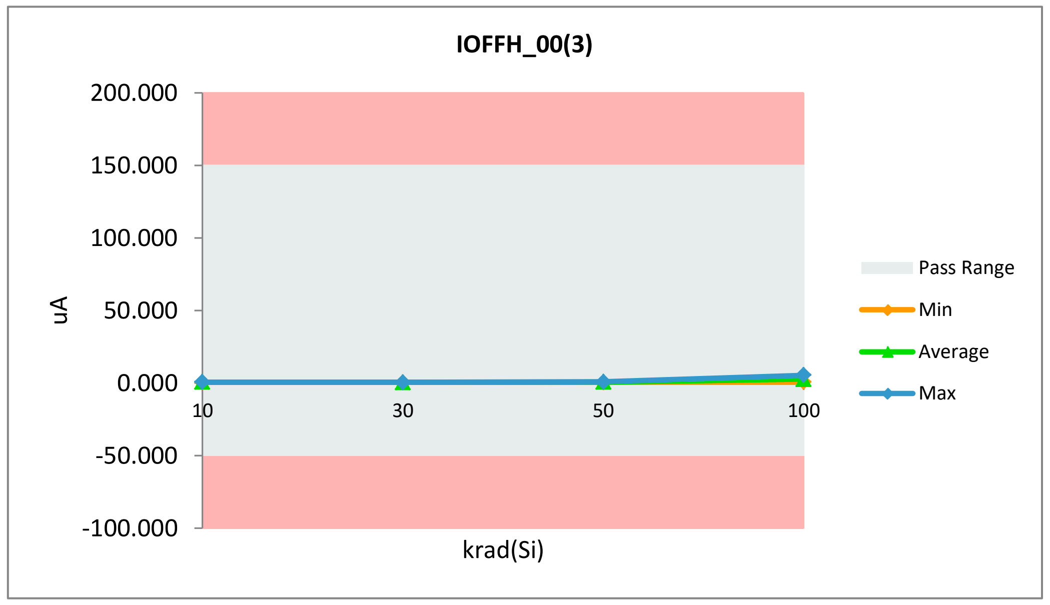


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.618	0.647	-0.029
10	5	0.618	0.629	-0.010
10	7	0.674	0.740	-0.066
10	11	0.693	0.703	-0.010
10	15	0.711	0.796	-0.085
10	20	0.600	0.591	0.008
10	21	0.618	0.703	-0.085
10	24	0.786	0.685	0.102
30	1	0.618	0.610	0.009
30	5	0.618	0.610	0.009
30	7	0.674	0.535	0.139
30	11	0.693	0.610	0.083
30	15	0.711	0.610	0.102
30	20	0.600	0.535	0.064
30	21	0.618	0.610	0.009
30	24	0.786	0.610	0.176
50	1	0.618	0.654	-0.036
50	5	0.618	0.710	-0.092
50	7	0.674	0.729	-0.055
50	11	0.693	0.710	-0.018
50	15	0.711	0.636	0.076
50	20	0.600	0.673	-0.074
50	21	0.618	0.636	-0.018
50	24	0.786	0.860	-0.074
100	3	0.730	5.614	-4.884
100	8	0.749	4.422	-3.673
100	12	0.786	0.846	-0.060
100	13	0.674	0.846	-0.171
100	16	0.730	4.422	-3.692
100	17	0.618	2.038	-1.420
100	18	0.618	3.230	-2.612
100	19	0.786	0.846	-0.060
	Max	0.786	5.614	0.176
	Average	0.676	1.190	-0.514
	Min	0.600	0.535	-4.884
	Std Dev	0.065	1.302	1.289

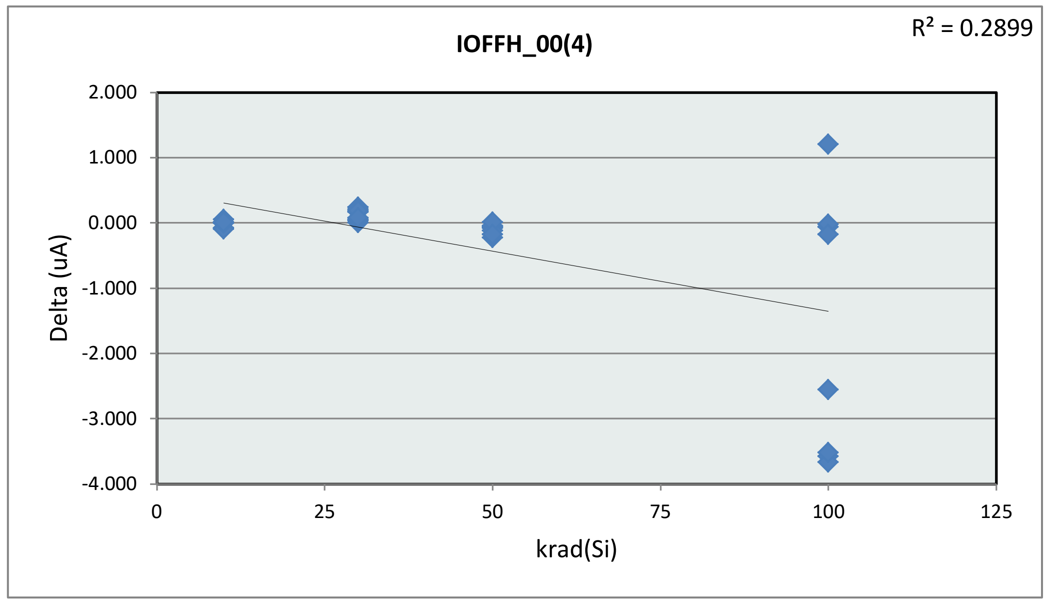


	IOFFH_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.591	0.535	0.636	0.846
Average	0.687	0.591	0.701	2.783
Max	0.796	0.610	0.860	5.614
UL	150.000	150.000	150.000	150.000

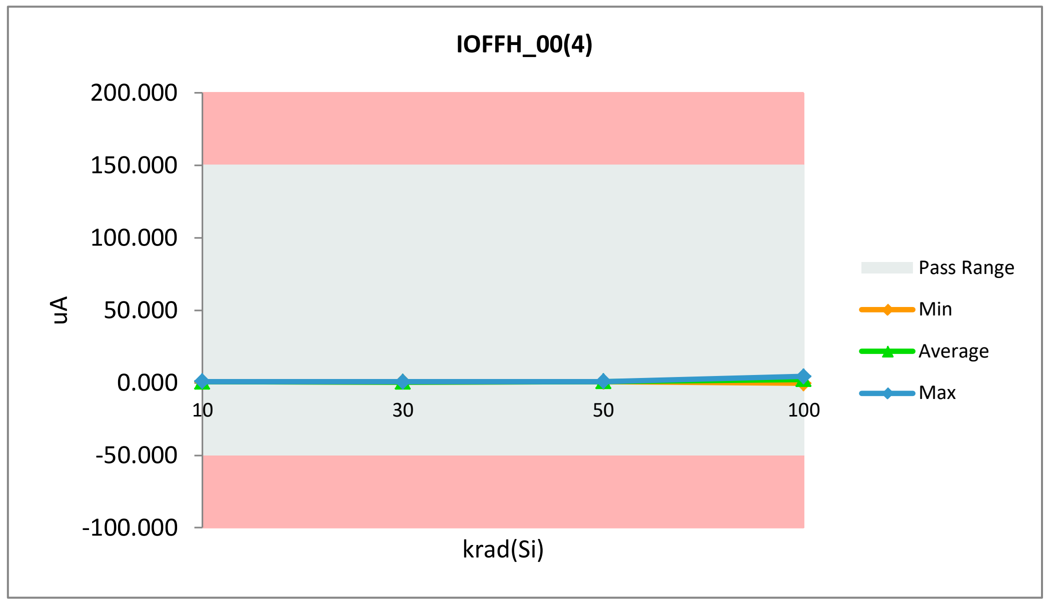


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.632	0.711	-0.079
10	5	0.799	0.785	0.014
10	7	0.613	0.692	-0.079
10	11	0.799	0.748	0.051
10	15	0.837	0.841	-0.004
10	20	0.595	0.692	-0.097
10	21	0.744	0.748	-0.004
10	24	0.706	0.692	0.014
30	1	0.632	0.633	-0.001
30	5	0.799	0.558	0.241
30	7	0.613	0.558	0.055
30	11	0.799	0.633	0.167
30	15	0.837	0.633	0.204
30	20	0.595	0.558	0.037
30	21	0.744	0.558	0.185
30	24	0.706	0.633	0.074
50	1	0.632	0.862	-0.230
50	5	0.799	0.862	-0.062
50	7	0.613	0.657	-0.044
50	11	0.799	0.862	-0.062
50	15	0.837	0.917	-0.081
50	20	0.595	0.713	-0.118
50	21	0.744	0.731	0.012
50	24	0.706	0.880	-0.174
100	3	0.781	4.358	-3.577
100	8	0.688	4.358	-3.670
100	12	0.725	0.787	-0.062
100	13	0.762	0.787	-0.025
100	16	0.837	4.358	-3.521
100	17	0.613	0.787	-0.174
100	18	0.613	3.168	-2.555
100	19	0.799	-0.403	1.203
	Max	0.837	4.358	1.203
	Average	0.719	1.105	-0.386
	Min	0.595	-0.403	-3.670
	Std Dev	0.087	1.171	1.167



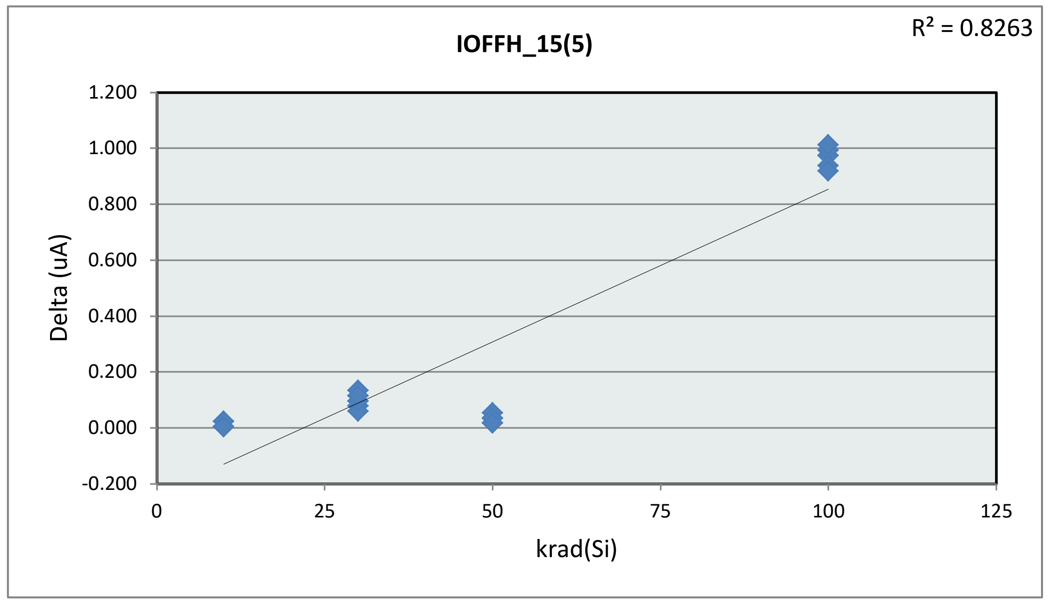
	IOFFH_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.692	0.558	0.657	-0.403
Average	0.739	0.595	0.811	2.275
Max	0.841	0.633	0.917	4.358
UL	150.000	150.000	150.000	150.000



LDR Biased TID Report
SN55LVCP22A-SP

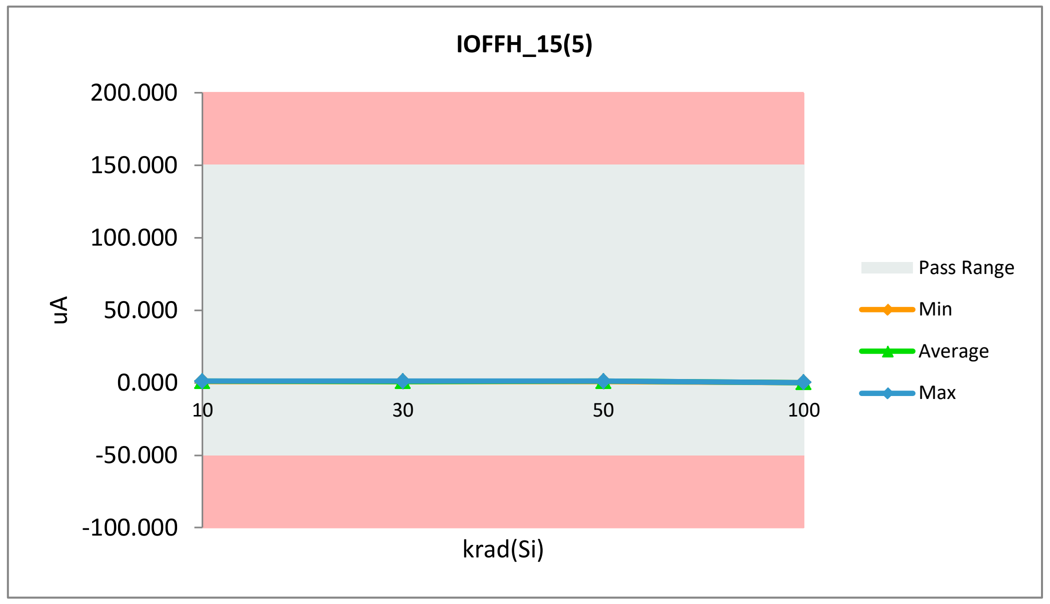
	IOFFH_15(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.026	1.022	0.004
10	5	1.045	1.041	0.004
10	7	1.008	0.985	0.023
10	11	1.045	1.022	0.023
10	15	1.064	1.041	0.023
10	20	0.971	0.966	0.004
10	21	1.008	1.004	0.004
10	24	1.026	1.022	0.004
30	1	1.026	0.911	0.115
30	5	1.045	0.911	0.133
30	7	1.008	0.911	0.096
30	11	1.045	0.911	0.133
30	15	1.064	0.986	0.078
30	20	0.971	0.911	0.059
30	21	1.008	0.911	0.096
30	24	1.026	0.911	0.115
50	1	1.026	1.010	0.017
50	5	1.045	1.010	0.035
50	7	1.008	0.973	0.035
50	11	1.045	1.010	0.035
50	15	1.064	1.010	0.054
50	20	0.971	0.954	0.017
50	21	1.008	0.973	0.035
50	24	1.026	1.010	0.017
100	3	1.045	0.071	0.974
100	8	1.045	0.071	0.974
100	12	1.064	0.071	0.993
100	13	1.045	0.071	0.974
100	16	1.064	0.071	0.993
100	17	1.008	0.071	0.937
100	18	0.989	0.071	0.919
100	19	1.082	0.071	1.012
	Max	1.082	1.041	1.012
	Average	1.029	0.749	0.279
	Min	0.971	0.071	0.004
	Std Dev	0.029	0.400	0.408



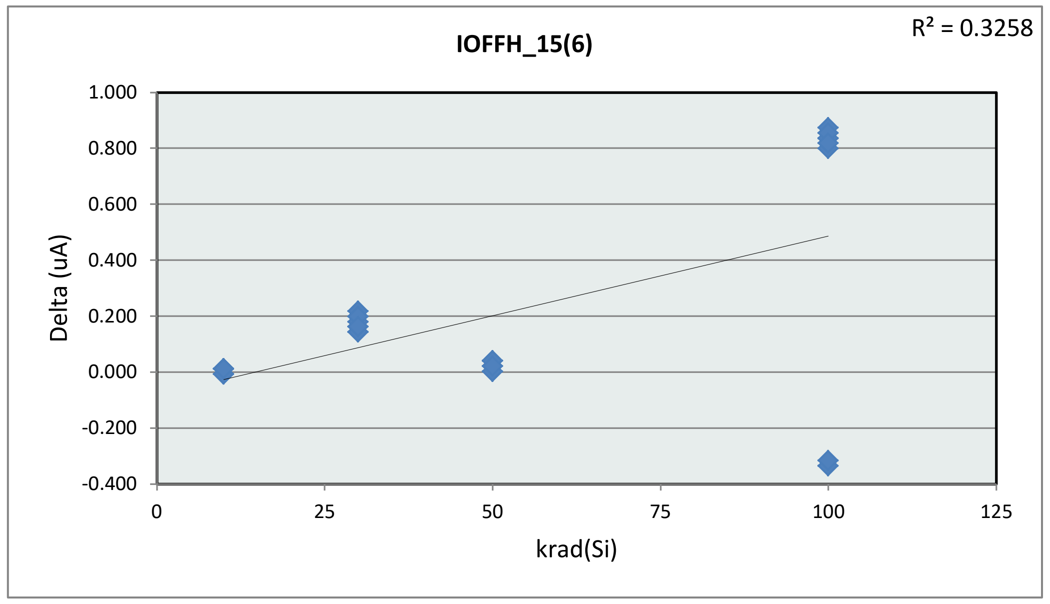
	IOFFH_15(5)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	uA
Min Limit	-50	uA

krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.966	0.911	0.954	0.071
Average	1.013	0.921	0.993	0.071
Max	1.041	0.986	1.010	0.071
UL	150.000	150.000	150.000	150.000

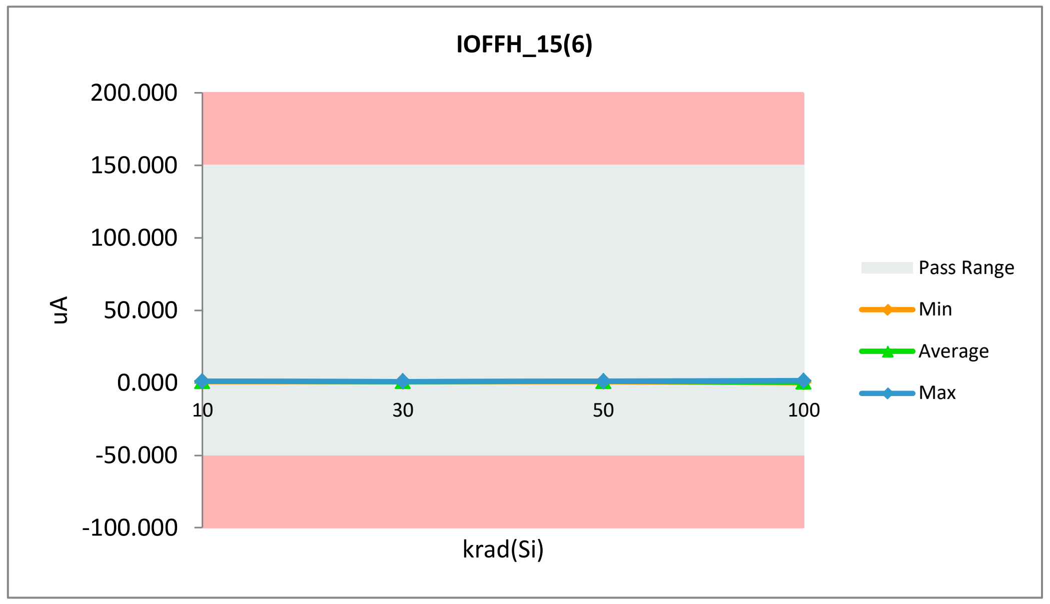


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_15(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.018	1.007	0.012
10	5	1.018	1.025	-0.007
10	7	1.000	0.988	0.012
10	11	1.018	1.025	-0.007
10	15	1.056	1.044	0.012
10	20	0.962	0.969	-0.007
10	21	1.000	0.988	0.012
10	24	1.037	1.025	0.012
30	1	1.018	0.801	0.217
30	5	1.018	0.875	0.143
30	7	1.000	0.801	0.199
30	11	1.018	0.875	0.143
30	15	1.056	0.875	0.180
30	20	0.962	0.801	0.162
30	21	1.000	0.801	0.199
30	24	1.037	0.875	0.161
50	1	1.018	1.016	0.002
50	5	1.018	0.998	0.020
50	7	1.000	0.961	0.039
50	11	1.018	0.998	0.020
50	15	1.056	1.016	0.039
50	20	0.962	0.961	0.002
50	21	1.000	0.961	0.039
50	24	1.037	1.016	0.020
100	3	1.018	0.182	0.836
100	8	1.018	0.182	0.836
100	12	1.056	0.182	0.873
100	13	1.037	1.373	-0.336
100	16	1.037	0.182	0.854
100	17	0.981	0.182	0.799
100	18	1.000	0.182	0.817
100	19	1.056	1.373	-0.317
	Max	1.056	1.373	0.873
	Average	1.017	0.829	0.187
	Min	0.962	0.182	-0.336
	Std Dev	0.026	0.340	0.338

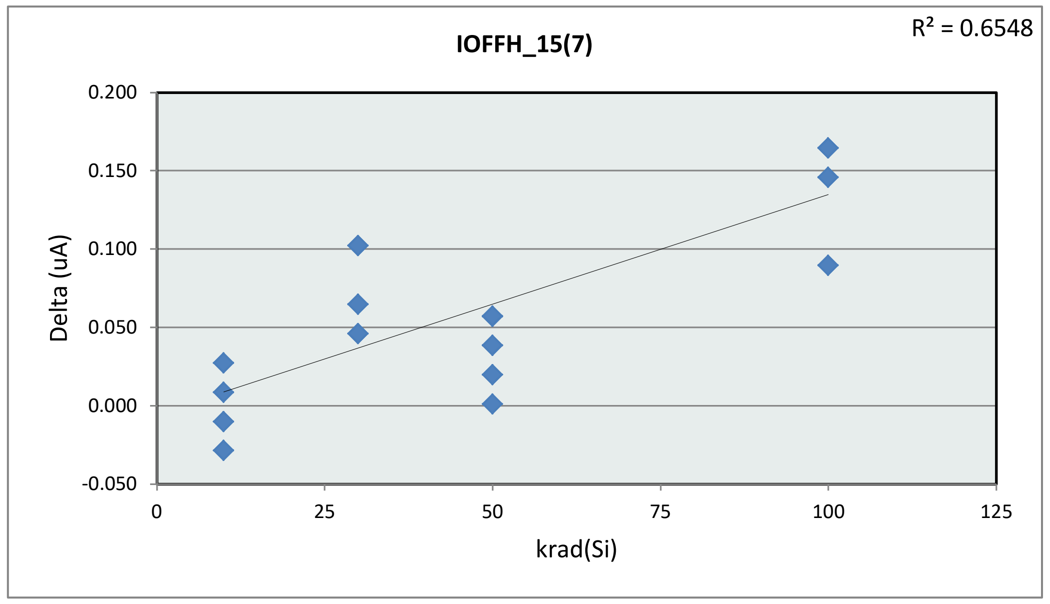


	IOFFH_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.969	0.801	0.961	0.182
Average	1.009	0.838	0.991	0.480
Max	1.044	0.875	1.016	1.373
UL	150.000	150.000	150.000	150.000

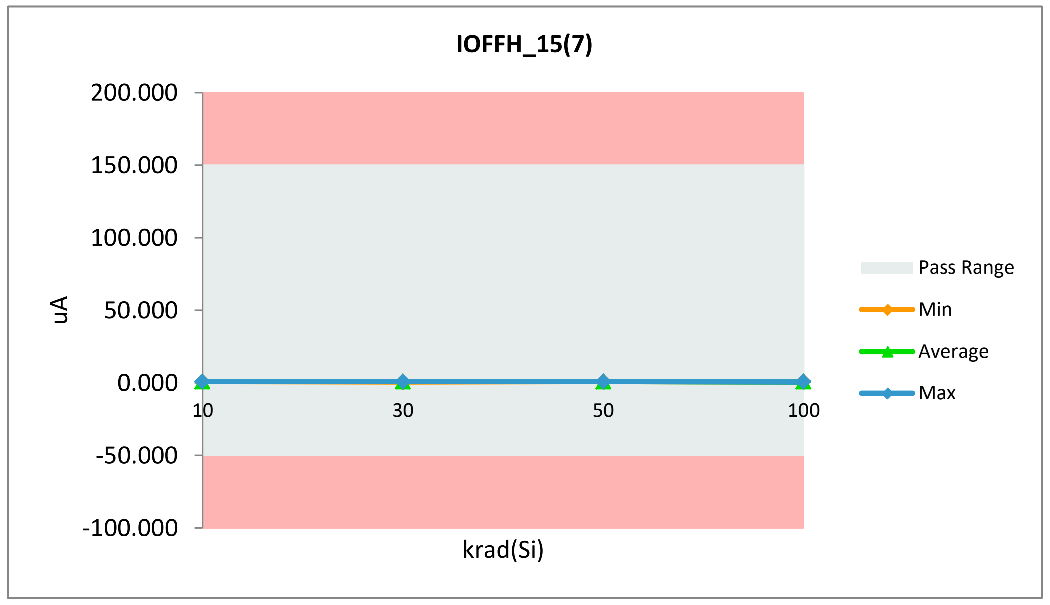


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFH_15(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.973	1.001	-0.029
10	5	1.010	0.983	0.027
10	7	0.935	0.945	-0.010
10	11	0.954	0.983	-0.029
10	15	1.047	1.020	0.027
10	20	0.954	0.945	0.008
10	21	0.954	0.964	-0.010
10	24	1.010	1.001	0.009
30	1	0.973	0.908	0.065
30	5	1.010	0.908	0.102
30	7	0.935	0.833	0.102
30	11	0.954	0.908	0.046
30	15	1.047	0.982	0.065
30	20	0.954	0.908	0.046
30	21	0.954	0.908	0.046
30	24	1.010	0.908	0.102
50	1	0.973	0.972	0.001
50	5	1.010	0.953	0.057
50	7	0.935	0.897	0.038
50	11	0.954	0.934	0.020
50	15	1.047	1.009	0.038
50	20	0.954	0.897	0.057
50	21	0.954	0.934	0.020
50	24	1.010	0.972	0.038
100	3	1.010	0.846	0.164
100	8	1.010	0.846	0.164
100	12	1.010	0.846	0.164
100	13	1.010	0.846	0.164
100	16	0.991	0.846	0.146
100	17	0.935	0.846	0.090
100	18	0.935	0.846	0.090
100	19	0.991	0.846	0.146
	Max	1.047	1.020	0.164
	Average	0.981	0.920	0.061
	Min	0.935	0.833	-0.029
	Std Dev	0.035	0.059	0.059



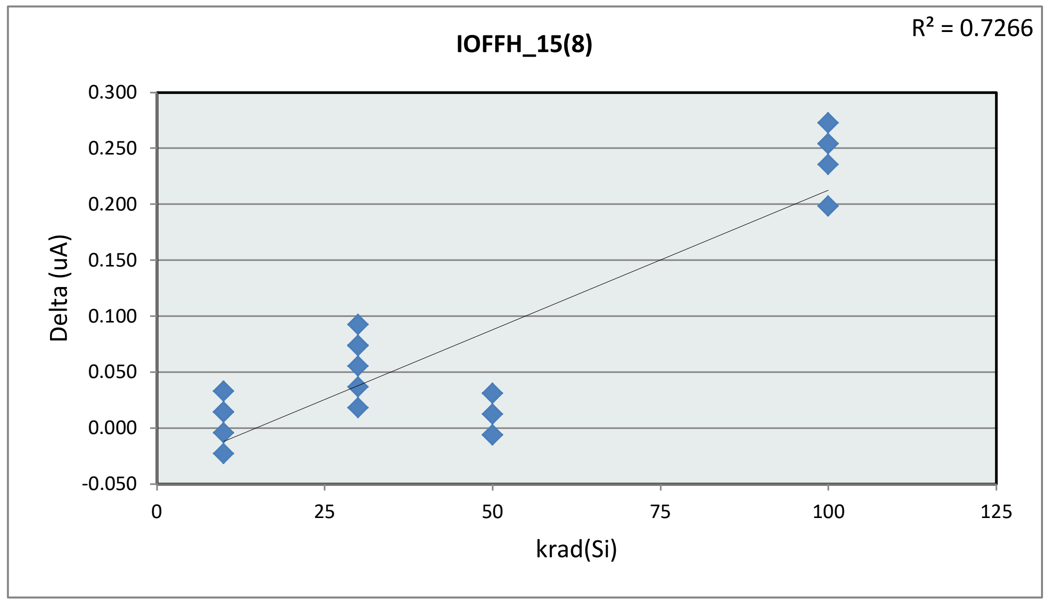
	IOFFH_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.945	0.833	0.897	0.846
Average	0.980	0.908	0.946	0.846
Max	1.020	0.982	1.009	0.846
UL	150.000	150.000	150.000	150.000



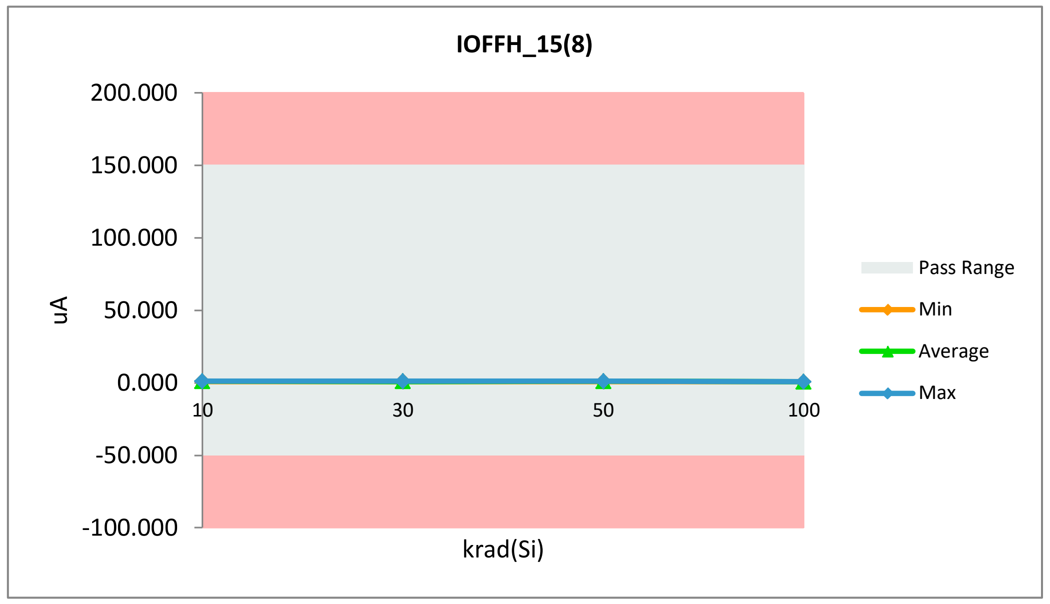
LDR Biased TID Report
SN55LVCP22A-SP

	IOFFH_15(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.004	0.990	0.014
10	5	1.023	1.008	0.014
10	7	0.948	0.971	-0.023
10	11	1.004	0.971	0.033
10	15	1.079	1.046	0.033
10	20	0.967	0.953	0.014
10	21	0.985	0.990	-0.004
10	24	1.023	1.008	0.014
30	1	1.004	0.930	0.074
30	5	1.023	0.930	0.092
30	7	0.948	0.930	0.018
30	11	1.004	0.930	0.074
30	15	1.079	1.005	0.074
30	20	0.967	0.930	0.037
30	21	0.985	0.930	0.055
30	24	1.023	0.930	0.092
50	1	1.004	0.992	0.012
50	5	1.023	1.029	-0.006
50	7	0.948	0.955	-0.006
50	11	1.004	0.973	0.031
50	15	1.079	1.048	0.031
50	20	0.967	0.955	0.012
50	21	0.985	0.992	-0.006
50	24	1.023	1.029	-0.006
100	3	1.041	0.787	0.254
100	8	1.041	0.787	0.254
100	12	1.060	0.787	0.273
100	13	1.023	0.787	0.236
100	16	1.041	0.787	0.254
100	17	0.985	0.787	0.198
100	18	0.985	0.787	0.198
100	19	1.060	0.787	0.273
	Max	1.079	1.048	0.273
	Average	1.010	0.929	0.082
	Min	0.948	0.787	-0.023
	Std Dev	0.037	0.090	0.100

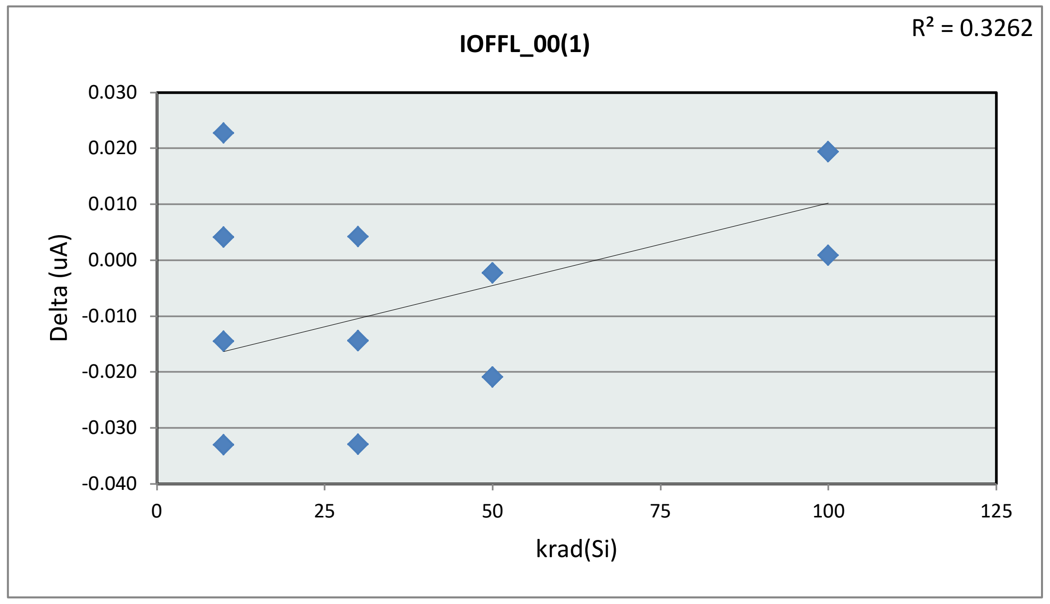


	IOFFH_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.953	0.930	0.955	0.787
Average	0.992	0.940	0.996	0.787
Max	1.046	1.005	1.048	0.787
UL	150.000	150.000	150.000	150.000

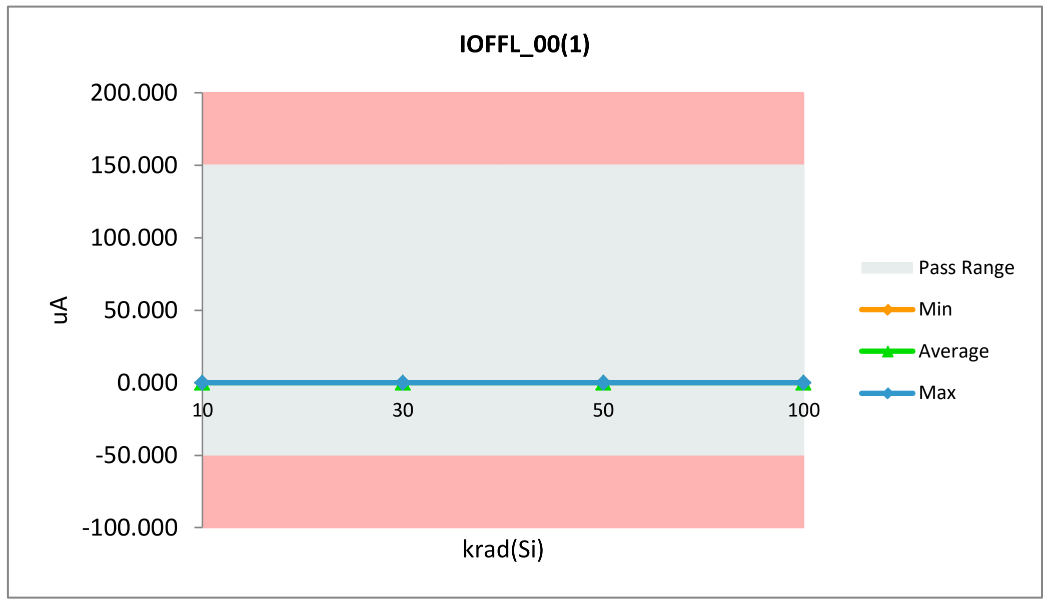


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_00(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.003	-0.001	0.004
10	5	-0.015	0.018	-0.033
10	7	0.003	0.018	-0.014
10	11	0.022	-0.001	0.023
10	15	0.003	-0.001	0.004
10	20	-0.015	0.018	-0.033
10	21	0.003	0.018	-0.014
10	24	0.003	-0.001	0.004
30	1	0.003	0.018	-0.014
30	5	-0.015	0.018	-0.033
30	7	0.003	0.018	-0.014
30	11	0.022	0.018	0.004
30	15	0.003	0.018	-0.014
30	20	-0.015	0.018	-0.033
30	21	0.003	0.018	-0.014
30	24	0.003	0.018	-0.014
50	1	0.003	0.006	-0.002
50	5	-0.015	0.006	-0.021
50	7	0.003	0.006	-0.002
50	11	0.022	0.024	-0.002
50	15	0.003	0.024	-0.021
50	20	-0.015	0.006	-0.021
50	21	0.003	0.006	-0.002
50	24	0.003	0.024	-0.021
100	3	0.003	-0.016	0.019
100	8	0.003	-0.016	0.019
100	12	0.003	-0.016	0.019
100	13	0.003	-0.016	0.019
100	16	-0.015	-0.016	0.001
100	17	-0.015	-0.016	0.001
100	18	0.003	-0.016	0.019
100	19	0.003	-0.016	0.019
	Max	0.022	0.024	0.023
	Average	0.000	0.006	-0.005
	Min	-0.015	-0.016	-0.033
	Std Dev	0.011	0.015	0.018



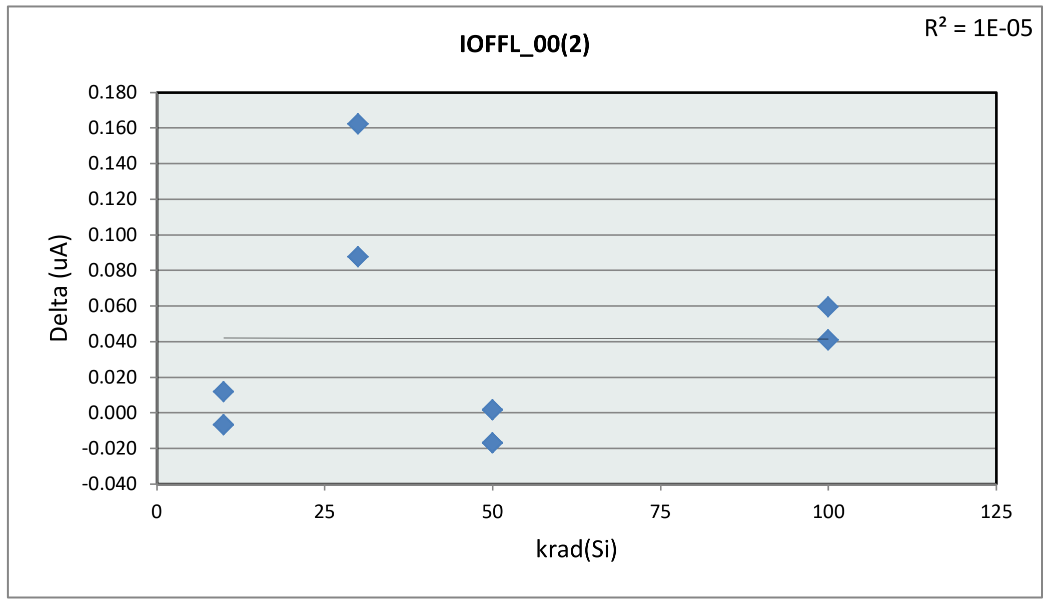
	IOFFL_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.001	0.018	0.006	-0.016
Average	0.009	0.018	0.013	-0.016
Max	0.018	0.018	0.024	-0.016
UL	150.000	150.000	150.000	150.000



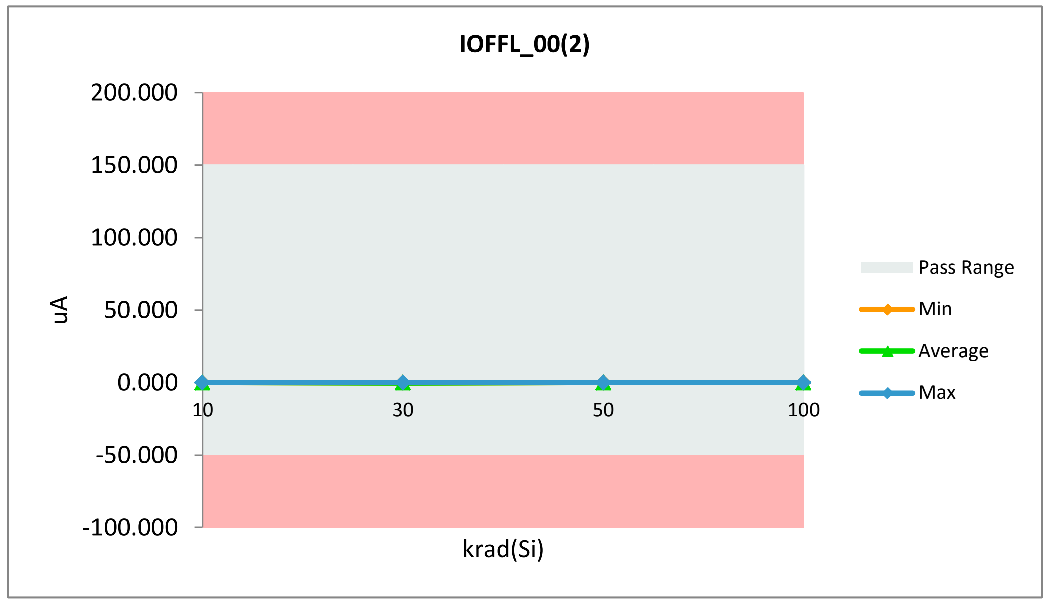
LDR Biased TID Report
SN55LVCP22A-SP

	IOFFL_00(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.005	-0.017	0.012
10	5	-0.005	0.001	-0.007
10	7	-0.005	-0.017	0.012
10	11	-0.005	0.001	-0.007
10	15	-0.005	0.001	-0.007
10	20	-0.005	0.001	-0.007
10	21	-0.005	0.001	-0.007
10	24	-0.005	0.001	-0.007
30	1	-0.005	-0.093	0.088
30	5	-0.005	-0.168	0.162
30	7	-0.005	-0.093	0.088
30	11	-0.005	-0.168	0.162
30	15	-0.005	-0.093	0.088
30	20	-0.005	-0.168	0.162
30	21	-0.005	-0.168	0.162
30	24	-0.005	-0.168	0.162
50	1	-0.005	0.012	-0.017
50	5	-0.005	-0.007	0.002
50	7	-0.005	0.012	-0.017
50	11	-0.005	0.012	-0.017
50	15	-0.005	-0.007	0.002
50	20	-0.005	-0.007	0.002
50	21	-0.005	0.012	-0.017
50	24	-0.005	-0.007	0.002
100	3	-0.005	-0.046	0.041
100	8	-0.005	-0.046	0.041
100	12	-0.005	-0.046	0.041
100	13	-0.005	-0.046	0.041
100	16	-0.005	-0.046	0.041
100	17	0.013	-0.046	0.059
100	18	-0.005	-0.046	0.041
100	19	-0.005	-0.046	0.041
	Max	0.013	0.012	0.162
	Average	-0.005	-0.047	0.042
	Min	-0.005	-0.168	-0.017
	Std Dev	0.003	0.061	0.061

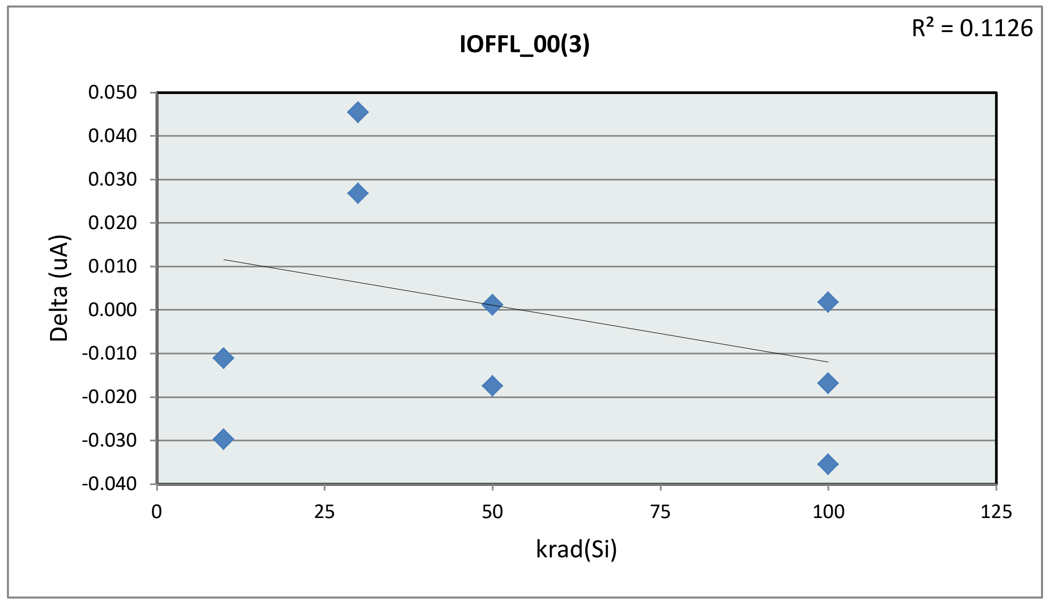


	IOFFL_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.017	-0.168	-0.007	-0.046
Average	-0.003	-0.140	0.002	-0.046
Max	0.001	-0.093	0.012	-0.046
UL	150.000	150.000	150.000	150.000

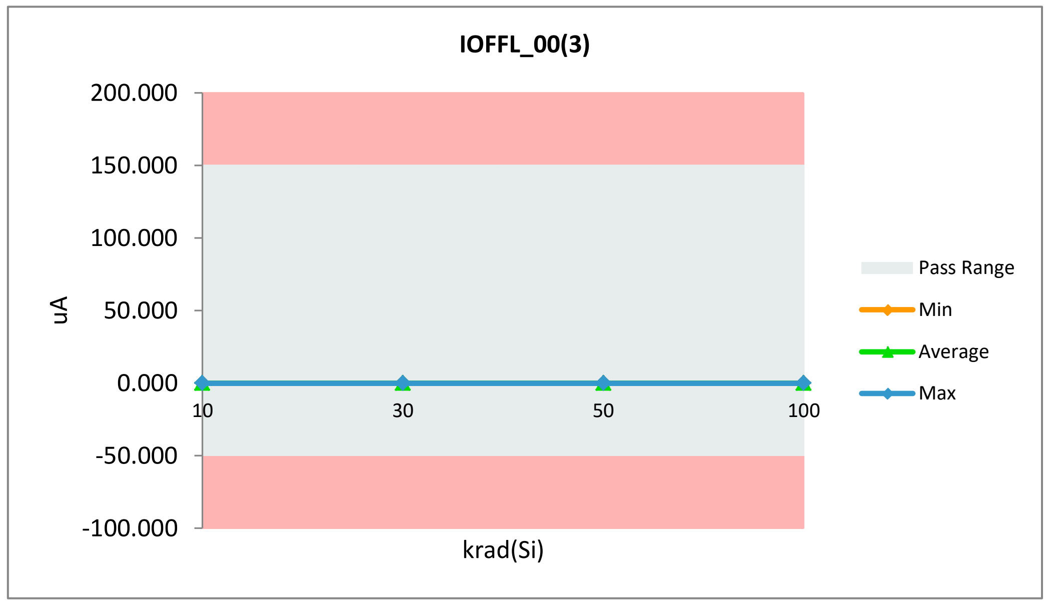


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_00(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.016	-0.005	-0.011
10	5	-0.035	-0.005	-0.030
10	7	-0.016	0.014	-0.030
10	11	-0.016	-0.005	-0.011
10	15	-0.016	-0.005	-0.011
10	20	-0.016	-0.005	-0.011
10	21	-0.016	-0.005	-0.011
10	24	-0.016	-0.005	-0.011
30	1	-0.016	-0.061	0.045
30	5	-0.035	-0.061	0.027
30	7	-0.016	-0.061	0.045
30	11	-0.016	-0.061	0.045
30	15	-0.016	-0.061	0.045
30	20	-0.016	-0.061	0.045
30	21	-0.016	-0.061	0.045
30	24	-0.016	-0.061	0.045
50	1	-0.016	-0.017	0.001
50	5	-0.035	-0.017	-0.017
50	7	-0.016	-0.017	0.001
50	11	-0.016	-0.017	0.001
50	15	-0.016	-0.017	0.001
50	20	-0.016	-0.017	0.001
50	21	-0.016	-0.017	0.001
50	24	-0.016	-0.017	0.001
100	3	-0.016	0.001	-0.017
100	8	-0.035	0.001	-0.035
100	12	-0.016	0.001	-0.017
100	13	-0.016	0.001	-0.017
100	16	-0.035	0.001	-0.035
100	17	-0.016	0.001	-0.017
100	18	-0.016	-0.018	0.002
100	19	-0.016	0.001	-0.017
	Max	-0.016	0.014	0.045
	Average	-0.019	-0.021	0.002
	Min	-0.035	-0.061	-0.035
	Std Dev	0.007	0.025	0.027

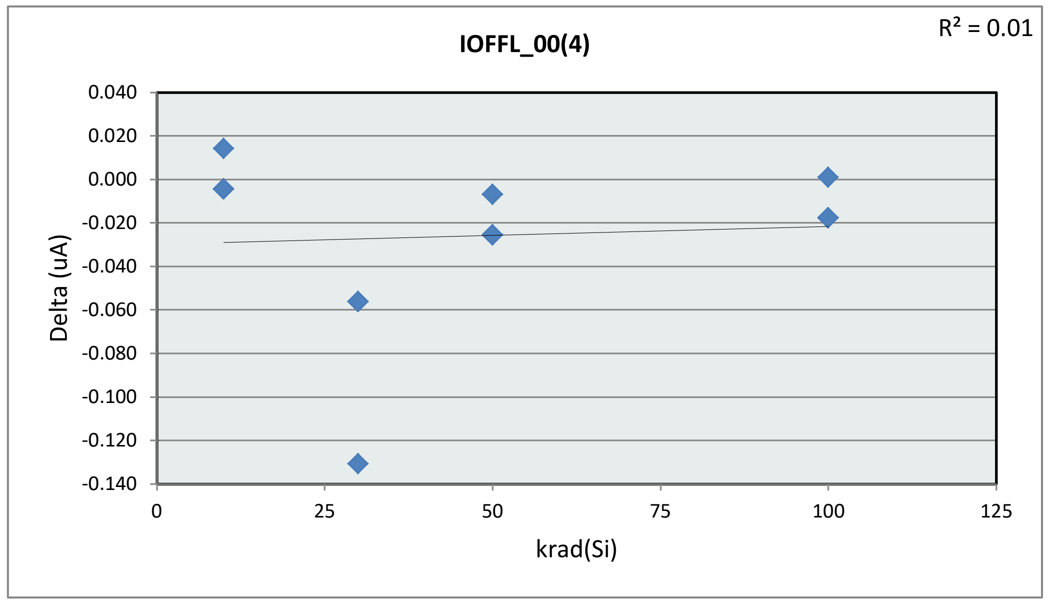


	IOFFL_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.005	-0.061	-0.017	-0.018
Average	-0.003	-0.061	-0.017	-0.002
Max	0.014	-0.061	-0.017	0.001
UL	150.000	150.000	150.000	150.000

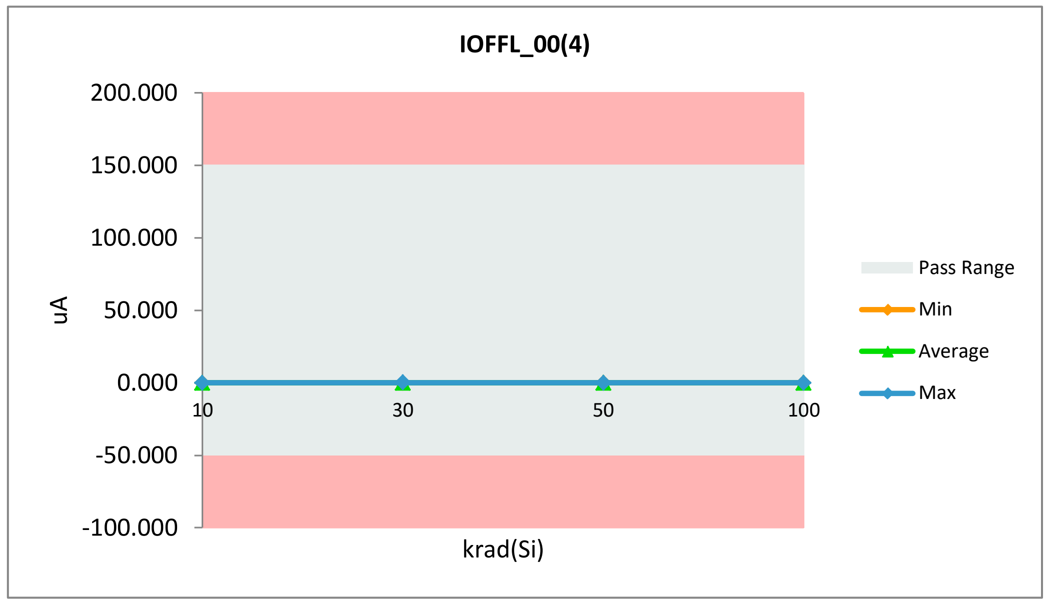


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.019	-0.015	-0.004
10	5	-0.019	-0.015	-0.004
10	7	-0.019	-0.033	0.014
10	11	-0.019	-0.015	-0.004
10	15	-0.019	-0.015	-0.004
10	20	-0.019	-0.015	-0.004
10	21	-0.019	-0.015	-0.004
10	24	-0.019	-0.015	-0.004
30	1	-0.019	0.037	-0.056
30	5	-0.019	0.037	-0.056
30	7	-0.019	0.037	-0.056
30	11	-0.019	0.037	-0.056
30	15	-0.019	0.112	-0.131
30	20	-0.019	0.037	-0.056
30	21	-0.019	0.037	-0.056
30	24	-0.019	0.037	-0.056
50	1	-0.019	0.006	-0.026
50	5	-0.019	0.006	-0.026
50	7	-0.019	0.006	-0.026
50	11	-0.019	0.006	-0.026
50	15	-0.019	0.006	-0.026
50	20	-0.019	-0.012	-0.007
50	21	-0.019	0.006	-0.026
50	24	-0.019	-0.012	-0.007
100	3	-0.019	-0.001	-0.018
100	8	-0.019	-0.020	0.001
100	12	-0.019	-0.001	-0.018
100	13	-0.019	-0.001	-0.018
100	16	-0.019	-0.001	-0.018
100	17	-0.019	-0.001	-0.018
100	18	-0.019	-0.001	-0.018
100	19	-0.019	-0.001	-0.018
	Max	-0.019	0.112	0.014
	Average	-0.019	0.007	-0.026
	Min	-0.019	-0.033	-0.131
	Std Dev	0.000	0.028	0.028

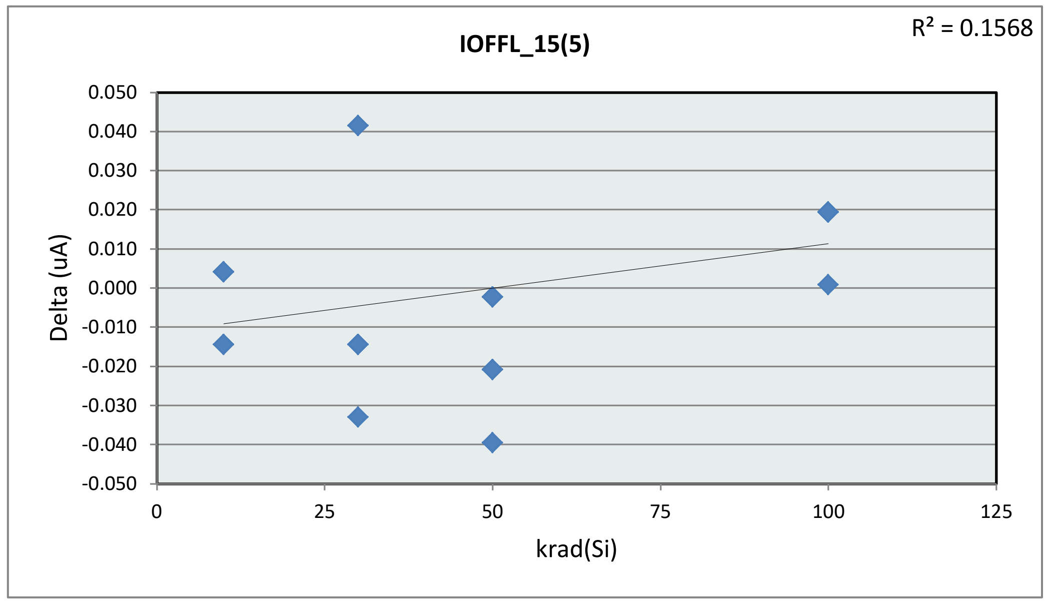


	IOFFL_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.033	0.037	-0.012	-0.020
Average	-0.017	0.046	0.002	-0.004
Max	-0.015	0.112	0.006	-0.001
UL	150.000	150.000	150.000	150.000

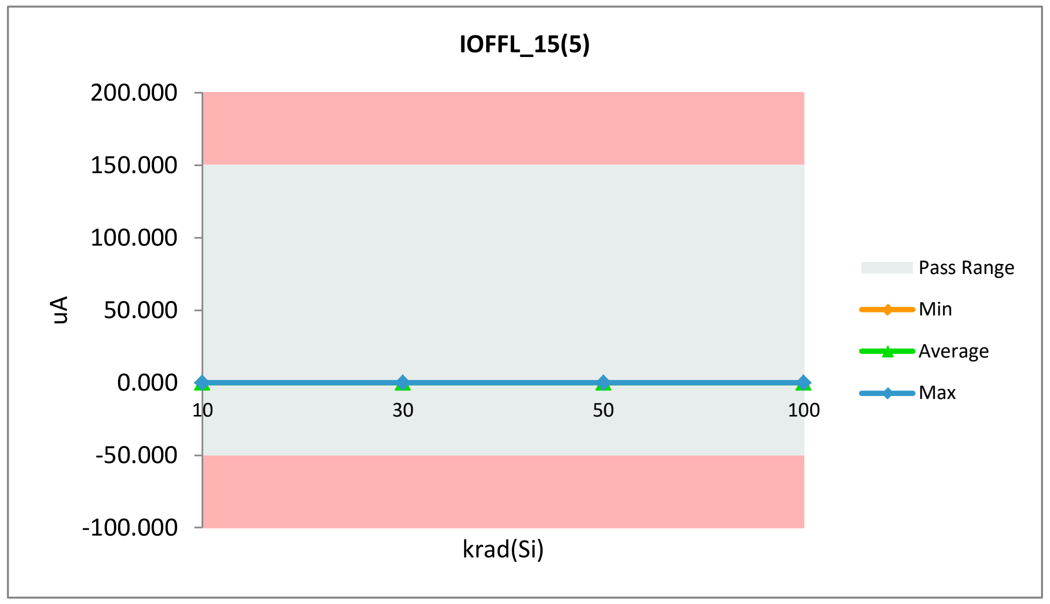


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_15(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.015	-0.001	-0.014
10	5	0.003	-0.001	0.004
10	7	-0.015	-0.019	0.004
10	11	0.003	0.018	-0.014
10	15	0.003	-0.001	0.004
10	20	-0.015	-0.001	-0.014
10	21	0.003	-0.001	0.004
10	24	0.003	-0.001	0.004
30	1	-0.015	-0.057	0.041
30	5	0.003	0.018	-0.014
30	7	-0.015	0.018	-0.033
30	11	0.003	0.018	-0.014
30	15	0.003	0.018	-0.014
30	20	-0.015	-0.057	0.041
30	21	0.003	0.018	-0.014
30	24	0.003	0.018	-0.014
50	1	-0.015	0.024	-0.039
50	5	0.003	0.024	-0.021
50	7	-0.015	-0.013	-0.002
50	11	0.003	0.006	-0.002
50	15	0.003	0.024	-0.021
50	20	-0.015	0.006	-0.021
50	21	0.003	0.006	-0.002
50	24	0.003	0.006	-0.002
100	3	0.003	-0.016	0.019
100	8	0.003	-0.016	0.019
100	12	0.003	-0.016	0.019
100	13	-0.015	-0.016	0.001
100	16	0.003	-0.016	0.019
100	17	0.003	-0.016	0.019
100	18	0.003	-0.016	0.019
100	19	0.003	-0.016	0.019
	Max	0.003	0.024	0.041
	Average	-0.002	-0.002	-0.001
	Min	-0.015	-0.057	-0.039
	Std Dev	0.009	0.021	0.020

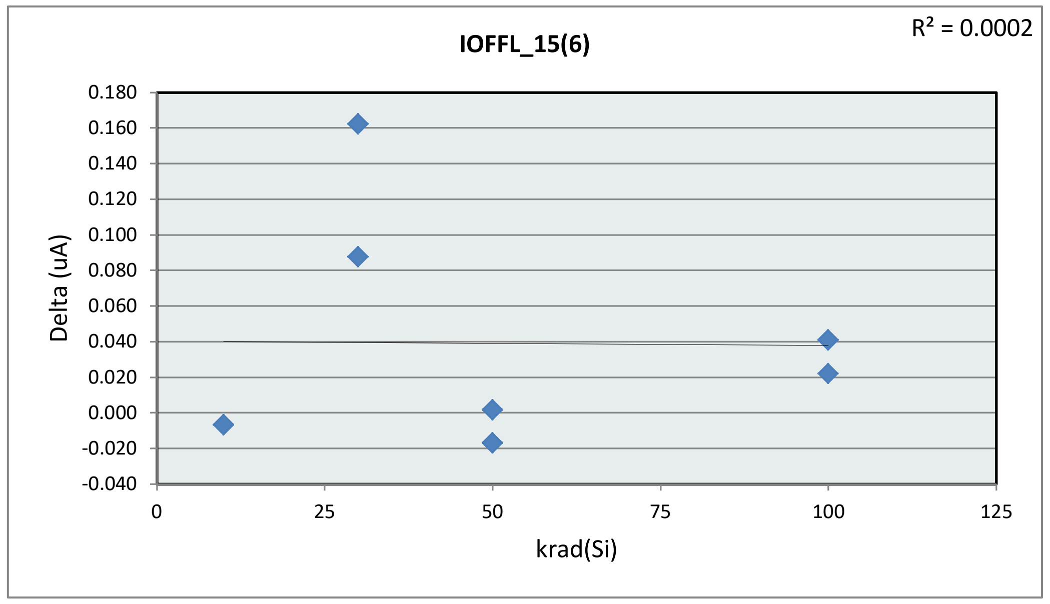


	IOFFL_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.019	-0.057	-0.013	-0.016
Average	-0.001	-0.001	0.010	-0.016
Max	0.018	0.018	0.024	-0.016
UL	150.000	150.000	150.000	150.000

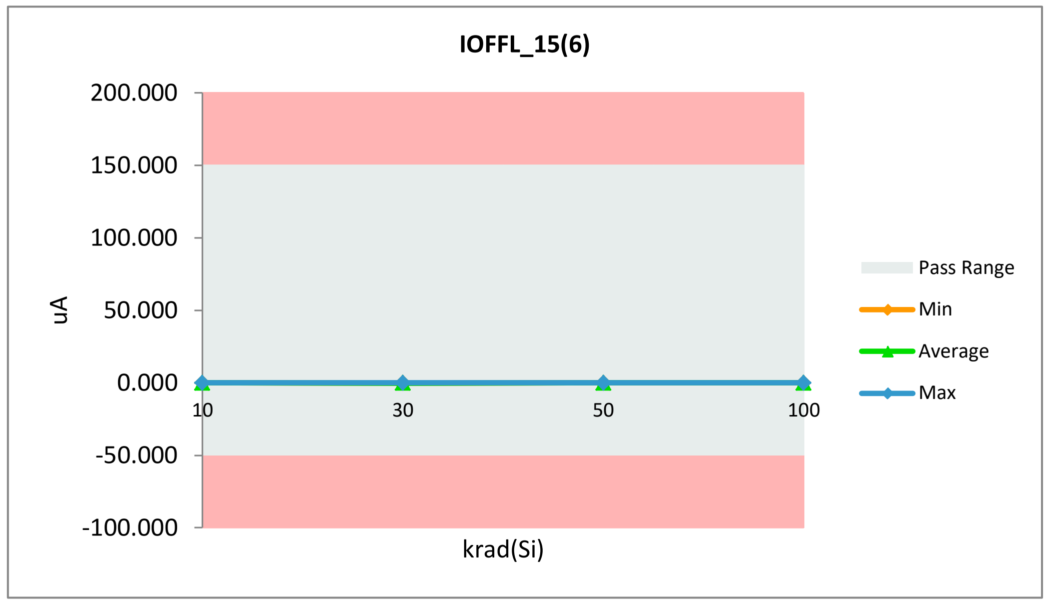


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_15(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.005	0.001	-0.007
10	5	-0.005	0.001	-0.007
10	7	-0.005	0.001	-0.007
10	11	-0.005	0.001	-0.007
10	15	-0.005	0.001	-0.007
10	20	-0.005	0.001	-0.007
10	21	-0.005	0.001	-0.007
10	24	-0.005	0.001	-0.007
30	1	-0.005	-0.168	0.162
30	5	-0.005	-0.168	0.162
30	7	-0.005	-0.093	0.088
30	11	-0.005	-0.093	0.088
30	15	-0.005	-0.093	0.088
30	20	-0.005	-0.168	0.162
30	21	-0.005	-0.168	0.162
30	24	-0.005	-0.168	0.162
50	1	-0.005	0.012	-0.017
50	5	-0.005	0.012	-0.017
50	7	-0.005	-0.007	0.002
50	11	-0.005	0.012	-0.017
50	15	-0.005	0.012	-0.017
50	20	-0.005	0.012	-0.017
50	21	-0.005	-0.007	0.002
50	24	-0.005	-0.007	0.002
100	3	-0.005	-0.046	0.041
100	8	-0.005	-0.046	0.041
100	12	-0.005	-0.046	0.041
100	13	-0.005	-0.046	0.041
100	16	-0.005	-0.027	0.022
100	17	-0.005	-0.046	0.041
100	18	-0.005	-0.046	0.041
100	19	-0.005	-0.046	0.041
	Max	-0.005	0.012	0.162
	Average	-0.005	-0.044	0.039
	Min	-0.005	-0.168	-0.017
	Std Dev	0.000	0.062	0.062



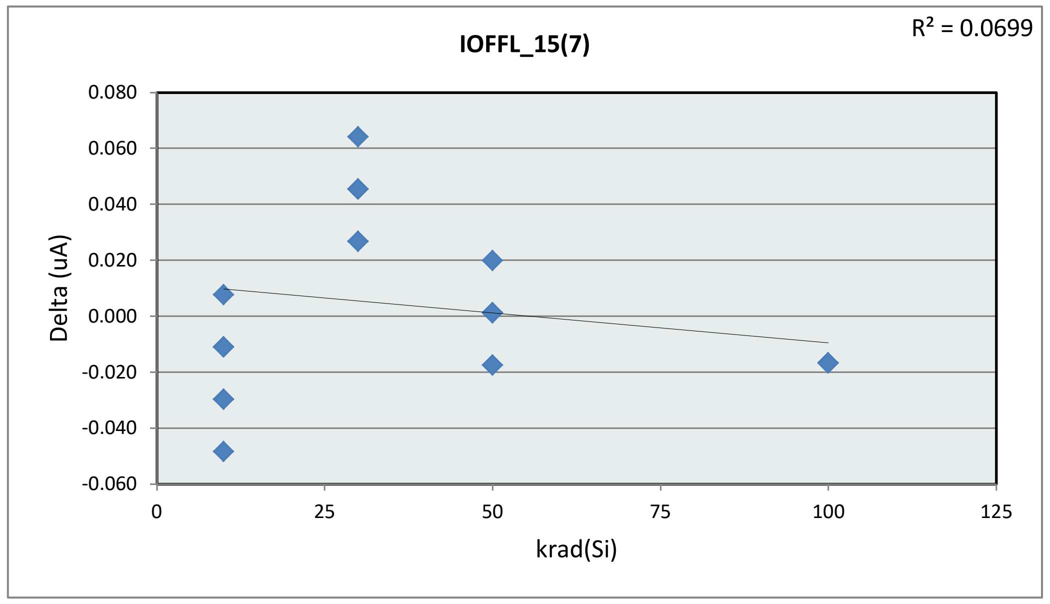
	IOFFL_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.001	-0.168	-0.007	-0.046
Average	0.001	-0.140	0.005	-0.044
Max	0.001	-0.093	0.012	-0.027
UL	150.000	150.000	150.000	150.000



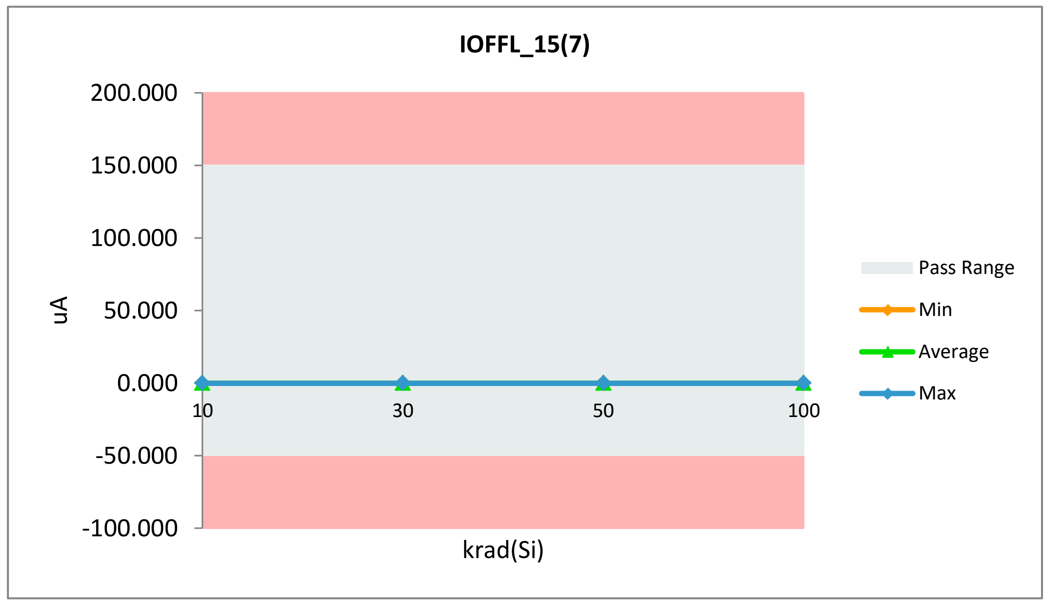
LDR Biased TID Report
SN55LVCP22A-SP

	IOFFL_15(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.035	0.014	-0.048
10	5	-0.016	-0.005	-0.011
10	7	-0.016	-0.005	-0.011
10	11	0.003	-0.005	0.008
10	15	-0.035	-0.005	-0.030
10	20	-0.016	-0.005	-0.011
10	21	-0.016	0.014	-0.030
10	24	-0.016	-0.005	-0.011
30	1	-0.035	-0.061	0.027
30	5	-0.016	-0.061	0.045
30	7	-0.016	-0.061	0.045
30	11	0.003	-0.061	0.064
30	15	-0.035	-0.061	0.027
30	20	-0.016	-0.061	0.045
30	21	-0.016	-0.061	0.045
30	24	-0.016	-0.061	0.045
50	1	-0.035	-0.017	-0.017
50	5	-0.016	-0.017	0.001
50	7	-0.016	-0.017	0.001
50	11	0.003	-0.017	0.020
50	15	-0.035	-0.017	-0.017
50	20	-0.016	-0.017	0.001
50	21	-0.016	-0.017	0.001
50	24	-0.016	-0.017	0.001
100	3	-0.016	0.001	-0.017
100	8	-0.016	0.001	-0.017
100	12	-0.016	0.001	-0.017
100	13	-0.016	0.001	-0.017
100	16	-0.016	0.001	-0.017
100	17	-0.016	0.001	-0.017
100	18	-0.016	0.001	-0.017
100	19	-0.016	0.001	-0.017
	Max	0.003	0.014	0.064
	Average	-0.018	-0.020	0.002
	Min	-0.035	-0.061	-0.048
	Std Dev	0.010	0.026	0.028

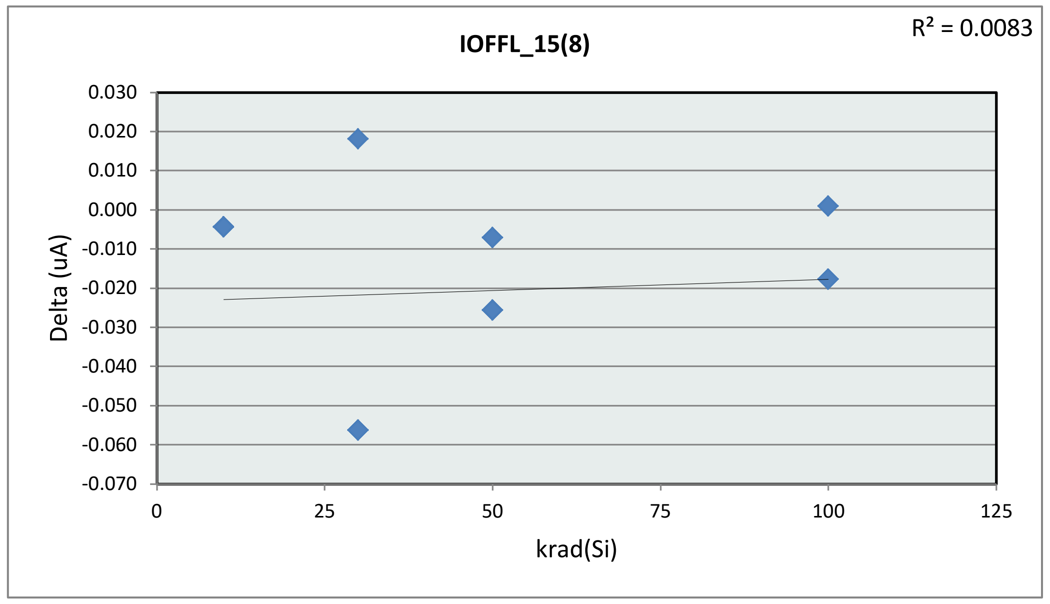


	IOFFL_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.005	-0.061	-0.017	0.001
Average	0.000	-0.061	-0.017	0.001
Max	0.014	-0.061	-0.017	0.001
UL	150.000	150.000	150.000	150.000

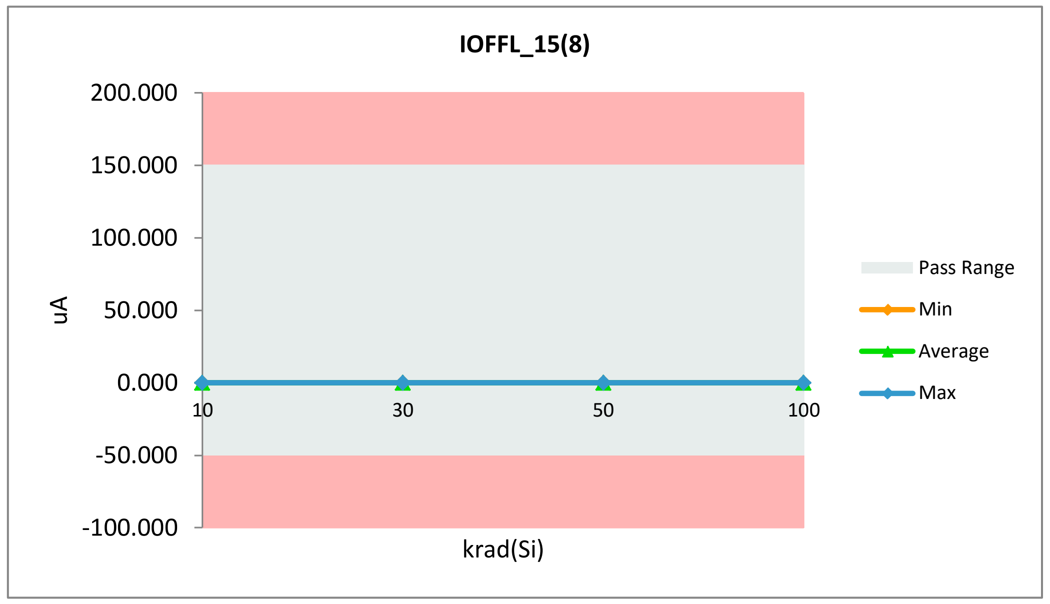


LDR Biased TID Report
SN55LVCP22A-SP

		IOFFL_15(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.019	-0.015	-0.004
10	5	-0.019	-0.015	-0.004
10	7	-0.019	-0.015	-0.004
10	11	-0.019	-0.015	-0.004
10	15	-0.019	-0.015	-0.004
10	20	-0.019	-0.015	-0.004
10	21	-0.019	-0.015	-0.004
10	24	-0.019	-0.015	-0.004
30	1	-0.019	0.037	-0.056
30	5	-0.019	0.037	-0.056
30	7	-0.019	0.037	-0.056
30	11	-0.019	0.037	-0.056
30	15	-0.019	0.037	-0.056
30	20	-0.019	0.037	-0.056
30	21	-0.019	-0.037	0.018
30	24	-0.019	0.037	-0.056
50	1	-0.019	-0.012	-0.007
50	5	-0.019	-0.012	-0.007
50	7	-0.019	0.006	-0.026
50	11	-0.019	0.006	-0.026
50	15	-0.019	-0.012	-0.007
50	20	-0.019	0.006	-0.026
50	21	-0.019	0.006	-0.026
50	24	-0.019	0.006	-0.026
100	3	-0.019	-0.001	-0.018
100	8	-0.019	-0.020	0.001
100	12	-0.019	-0.001	-0.018
100	13	-0.019	-0.001	-0.018
100	16	-0.019	-0.001	-0.018
100	17	-0.019	-0.001	-0.018
100	18	-0.019	-0.020	0.001
100	19	-0.019	-0.001	-0.018
	Max	-0.019	0.037	0.018
	Average	-0.019	0.002	-0.021
	Min	-0.019	-0.037	-0.056
	Std Dev	0.000	0.021	0.021

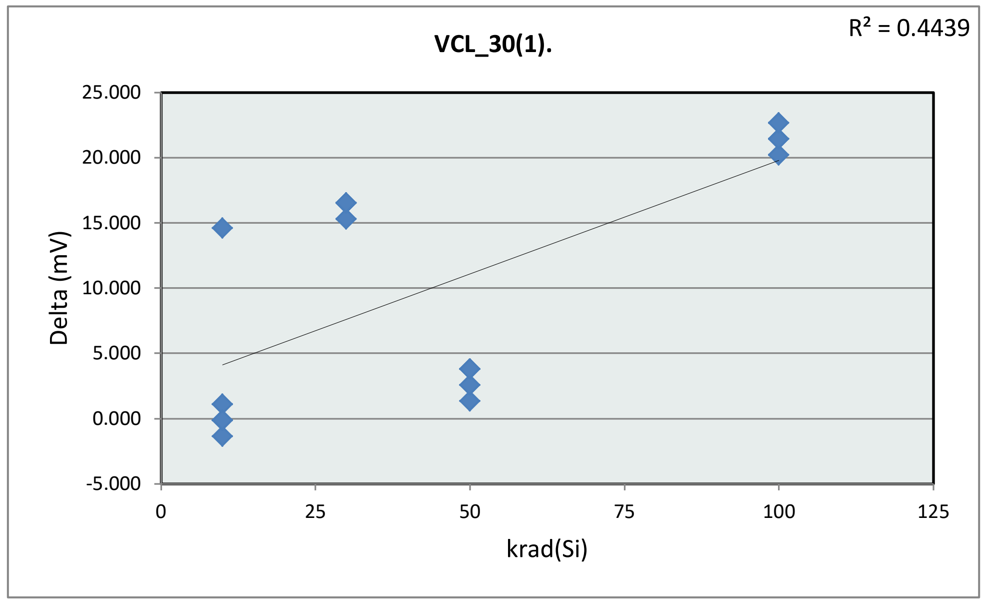


	IOFFL_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.015	-0.037	-0.012	-0.020
Average	-0.015	0.028	-0.001	-0.006
Max	-0.015	0.037	0.006	-0.001
UL	150.000	150.000	150.000	150.000

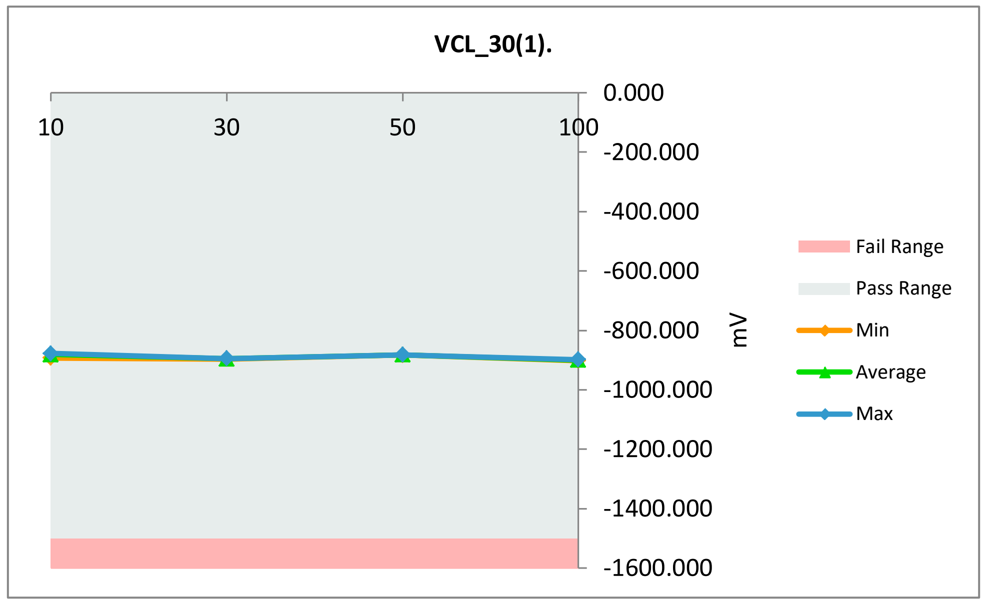


LDR Biased TID Report
SN55LVCP22A-SP

		VCL_30(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-880.424	-879.038	-1.386
10	5	-880.424	-881.495	1.071
10	7	-879.195	-880.267	1.072
10	11	-879.195	-879.038	-0.157
10	15	-877.967	-892.552	14.585
10	20	-877.967	-877.810	-0.157
10	21	-879.195	-879.038	-0.157
10	24	-879.195	-879.038	-0.157
30	1	-880.424	-895.707	15.283
30	5	-880.424	-896.928	16.504
30	7	-879.195	-895.707	16.512
30	11	-879.195	-894.486	15.291
30	15	-877.967	-894.486	16.519
30	20	-877.967	-894.486	16.519
30	21	-879.195	-895.707	16.512
30	24	-879.195	-895.707	16.512
50	1	-880.424	-882.975	2.551
50	5	-880.424	-881.747	1.323
50	7	-879.195	-882.975	3.780
50	11	-879.195	-882.975	3.780
50	15	-877.967	-881.747	3.780
50	20	-877.967	-881.747	3.780
50	21	-879.195	-881.747	2.552
50	24	-879.195	-882.975	3.780
100	3	-879.195	-900.605	21.410
100	8	-879.195	-899.384	20.189
100	12	-877.967	-900.605	22.638
100	13	-879.195	-900.605	21.410
100	16	-876.738	-898.163	21.425
100	17	-879.195	-899.384	20.189
100	18	-879.195	-900.605	21.410
100	19	-879.195	-901.826	22.631
	Max	-876.738	-877.810	22.638
	Average	-879.080	-889.736	10.656
	Min	-880.424	-901.826	-1.386
	Std Dev	0.902	8.691	8.885

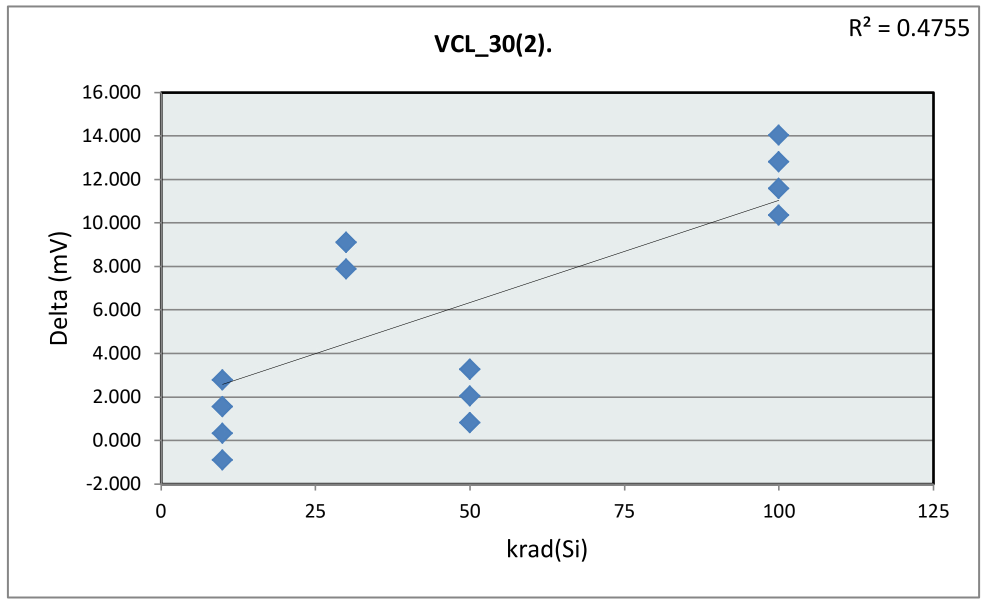


	VCL_30(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-1500 mV			
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-892.552	-896.928	-882.975	-901.826
Average	-881.035	-895.402	-882.361	-900.147
Max	-877.810	-894.486	-881.747	-898.163
UL				

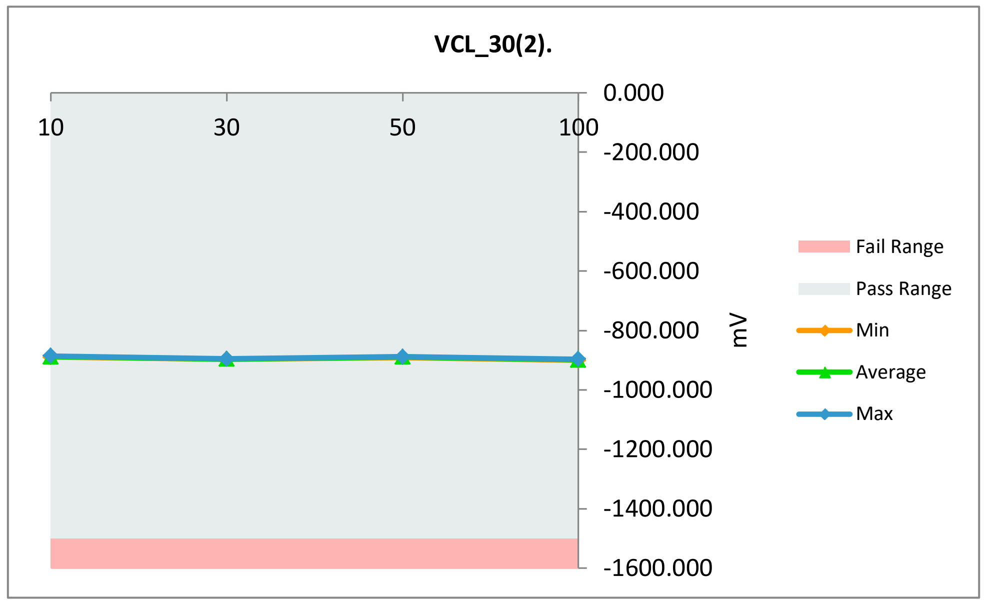


LDR Biased TID Report
SN55LVCP22A-SP

		VCL_30(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-889.031	-889.352	0.321
10	5	-887.804	-890.579	2.775
10	7	-886.577	-888.125	1.548
10	11	-886.577	-889.352	2.775
10	15	-886.577	-885.671	-0.906
10	20	-886.577	-888.125	1.548
10	21	-887.804	-889.352	1.548
10	24	-887.804	-889.352	1.548
30	1	-889.031	-896.899	7.868
30	5	-887.804	-896.899	9.095
30	7	-886.577	-895.677	9.100
30	11	-886.577	-895.677	9.100
30	15	-886.577	-895.677	9.100
30	20	-886.577	-895.677	9.100
30	21	-887.804	-896.899	9.095
30	24	-887.804	-896.899	9.095
50	1	-889.031	-889.845	0.814
50	5	-887.804	-888.618	0.814
50	7	-886.577	-889.845	3.268
50	11	-886.577	-889.845	3.268
50	15	-886.577	-888.618	2.041
50	20	-886.577	-889.845	3.268
50	21	-887.804	-888.618	0.814
50	24	-887.804	-891.071	3.267
100	3	-887.804	-899.376	11.572
100	8	-887.804	-898.155	10.351
100	12	-885.350	-899.376	14.026
100	13	-887.804	-900.597	12.793
100	16	-886.577	-896.934	10.357
100	17	-887.804	-899.376	11.572
100	18	-887.804	-899.376	11.572
100	19	-887.804	-900.597	12.793
	Max	-885.350	-885.671	14.026
	Average	-887.344	-893.447	6.103
	Min	-889.031	-900.597	-0.906
	Std Dev	0.868	4.630	4.629

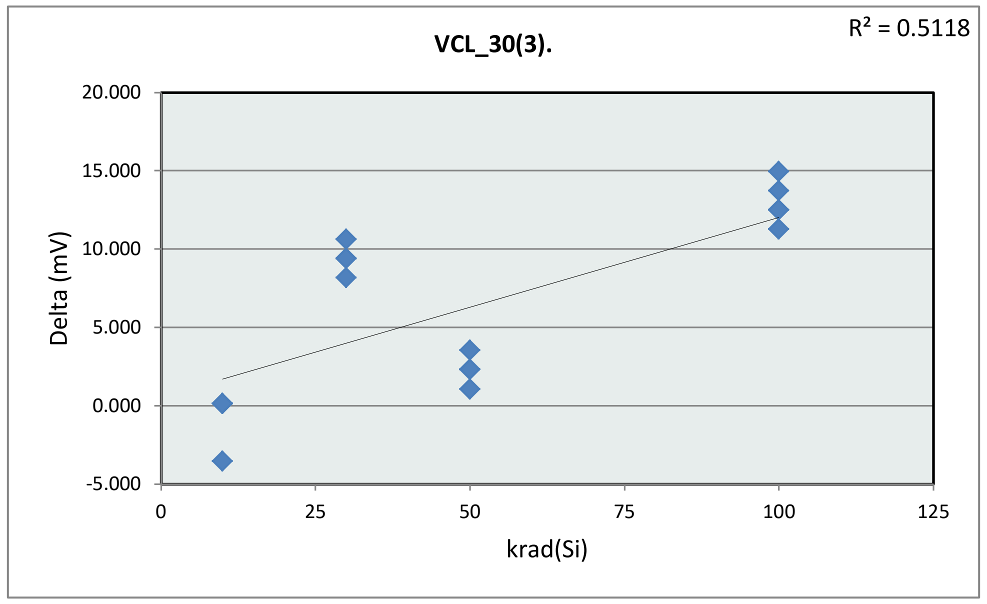


	VCL_30(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-890.579	-896.899	-891.071	-900.597
Average	-888.739	-896.288	-889.538	-899.223
Max	-885.671	-895.677	-888.618	-896.934
UL				

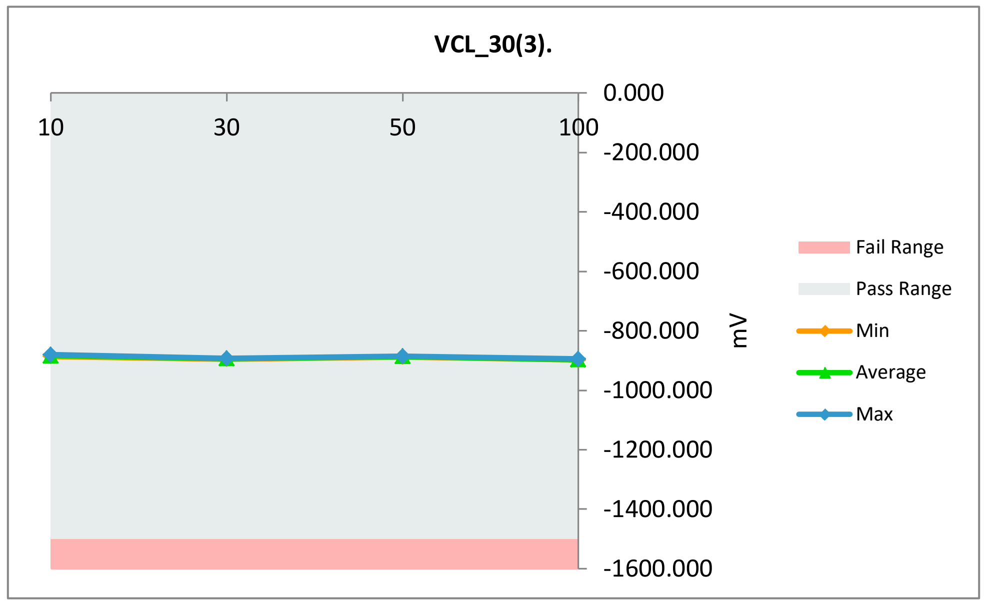


LDR Biased TID Report
SN55LVCP22A-SP

		VCL_30(3).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-884.749	-884.896	0.147
10	5	-885.978	-886.126	0.148
10	7	-884.749	-884.896	0.147
10	11	-884.749	-884.896	0.147
10	15	-883.519	-879.977	-3.542
10	20	-884.749	-884.896	0.147
10	21	-883.519	-883.667	0.148
10	24	-884.749	-884.896	0.147
30	1	-884.749	-894.136	9.387
30	5	-885.978	-895.357	9.379
30	7	-884.749	-894.136	9.387
30	11	-884.749	-894.136	9.387
30	15	-883.519	-892.915	9.396
30	20	-884.749	-892.915	8.166
30	21	-883.519	-894.136	10.617
30	24	-884.749	-895.357	10.608
50	1	-884.749	-888.274	3.525
50	5	-885.978	-887.045	1.067
50	7	-884.749	-887.045	2.296
50	11	-884.749	-887.045	2.296
50	15	-883.519	-885.815	2.296
50	20	-884.749	-885.815	1.066
50	21	-883.519	-885.815	2.296
50	24	-884.749	-887.045	2.296
100	3	-884.749	-897.233	12.484
100	8	-885.978	-897.233	11.255
100	12	-884.749	-897.233	12.484
100	13	-883.519	-898.453	14.934
100	16	-883.519	-894.791	11.272
100	17	-884.749	-897.233	12.484
100	18	-884.749	-897.233	12.484
100	19	-884.749	-898.453	13.704
	Max	-883.519	-879.977	14.934
	Average	-884.595	-890.597	6.002
	Min	-885.978	-898.453	-3.542
	Std Dev	0.749	5.492	5.452

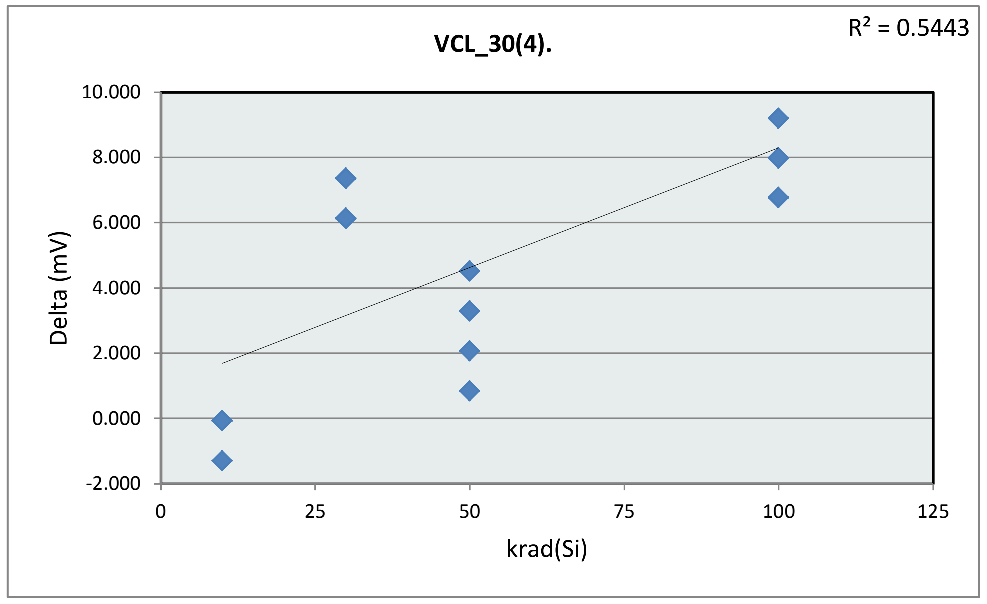


	VCL_30(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-1500	mV		
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-886.126	-895.357	-888.274	-898.453
Average	-884.281	-894.136	-886.737	-897.233
Max	-879.977	-892.915	-885.815	-894.791
UL				

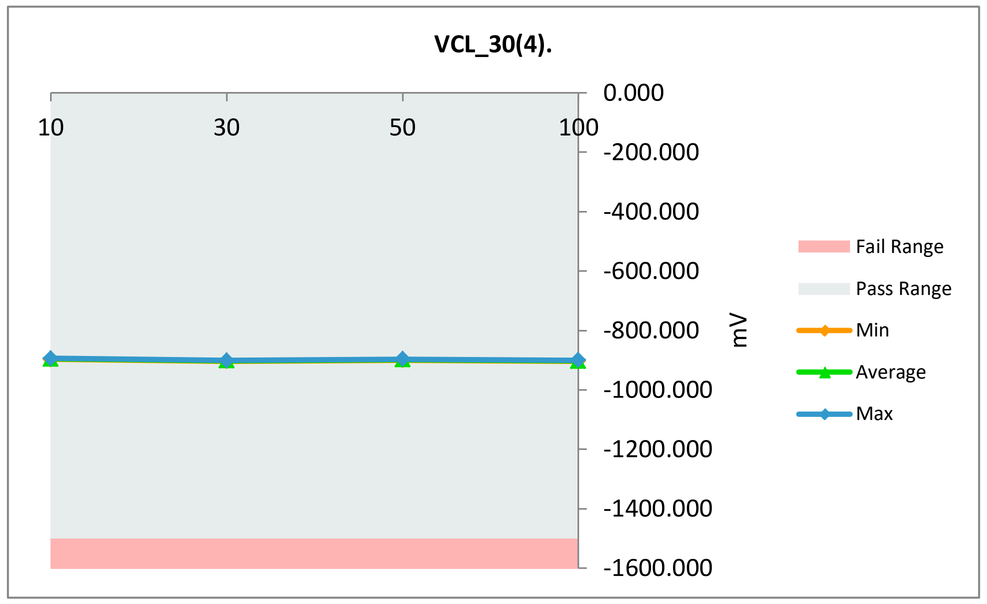


LDR Biased TID Report
SN55LVCP22A-SP

		VCL_30(4).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-1500	-1500	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-896.010	-895.938	-0.072
10	5	-897.239	-897.167	-0.072
10	7	-896.010	-894.710	-1.300
10	11	-894.781	-894.710	-0.071
10	15	-893.553	-893.481	-0.072
10	20	-894.781	-894.710	-0.071
10	21	-894.781	-894.710	-0.071
10	24	-896.010	-895.938	-0.072
30	1	-896.010	-902.135	6.125
30	5	-897.239	-903.355	6.116
30	7	-896.010	-902.135	6.125
30	11	-894.781	-900.915	6.134
30	15	-893.553	-900.915	7.362
30	20	-894.781	-900.915	6.134
30	21	-894.781	-902.135	7.354
30	24	-896.010	-903.355	7.345
50	1	-896.010	-900.535	4.525
50	5	-897.239	-898.078	0.839
50	7	-896.010	-899.306	3.296
50	11	-894.781	-899.306	4.525
50	15	-893.553	-898.078	4.525
50	20	-894.781	-898.078	3.297
50	21	-894.781	-896.849	2.068
50	24	-896.010	-899.306	3.296
100	3	-896.010	-903.979	7.969
100	8	-896.010	-902.759	6.749
100	12	-894.781	-902.759	7.978
100	13	-894.781	-903.979	9.198
100	16	-893.553	-900.319	6.766
100	17	-894.781	-902.759	7.978
100	18	-894.781	-903.979	9.198
100	19	-894.781	-903.979	9.198
	Max	-893.553	-893.481	9.198
	Average	-895.280	-899.727	4.447
	Min	-897.239	-903.979	-1.300
	Std Dev	1.028	3.316	3.378



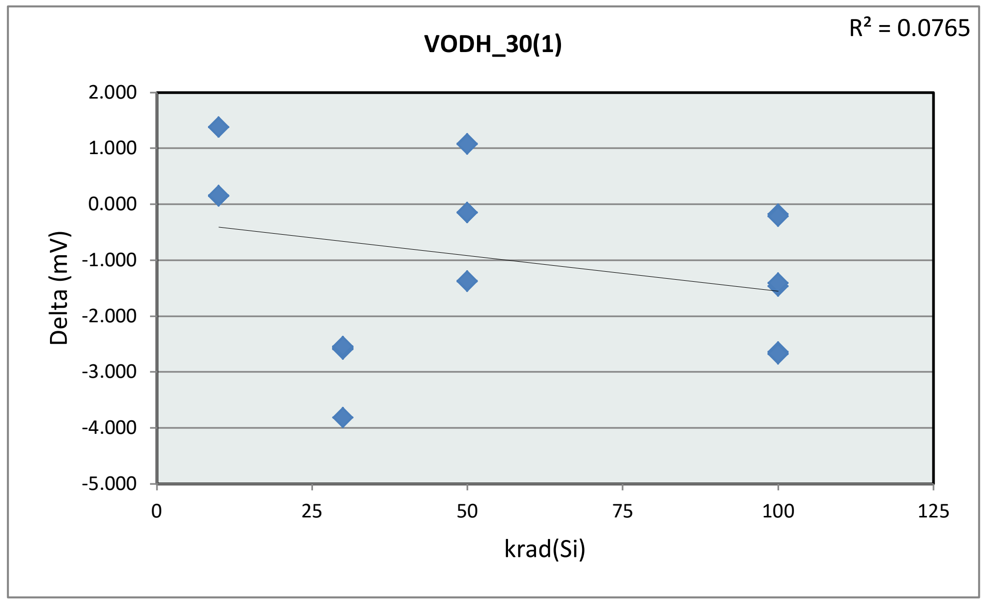
	VCL_30(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-1500 mV			
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-897.167	-903.355	-900.535	-903.979
Average	-895.171	-901.983	-898.692	-903.064
Max	-893.481	-900.915	-896.849	-900.319
UL				



LDR Biased TID Report
SN55LVCP22A-SP

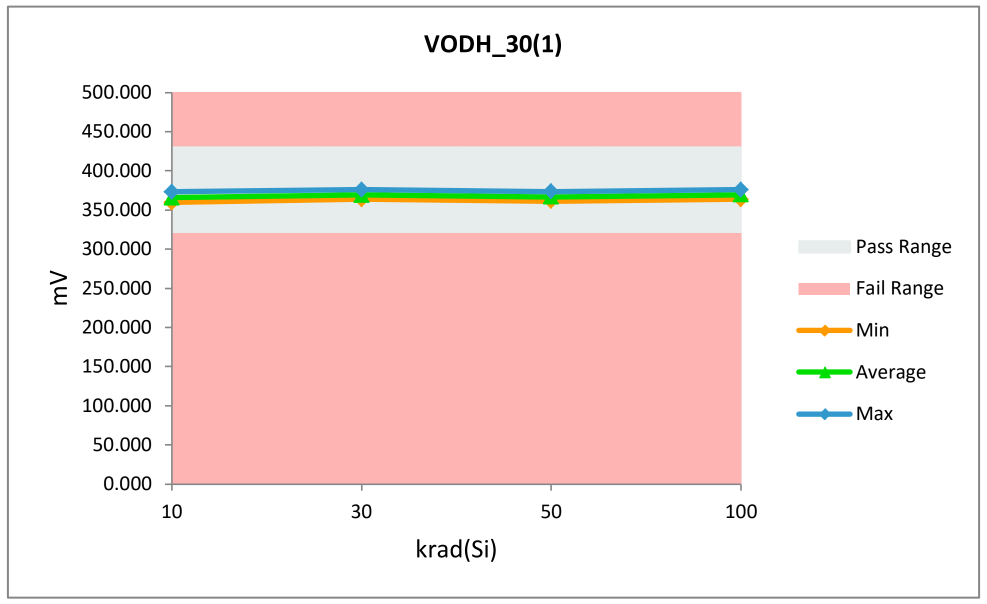
	VODH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	363.463	362.088	1.375
10	5	362.233	362.085	0.148
10	7	359.777	359.629	0.148
10	11	368.375	368.228	0.147
10	15	373.283	373.133	0.150
10	20	370.829	369.453	1.376
10	21	362.236	360.862	1.374
10	24	372.056	370.680	1.376
30	1	363.463	366.049	-2.586
30	5	362.233	364.822	-2.589
30	7	359.777	363.597	-3.820
30	11	368.375	370.945	-2.570
30	15	373.283	375.827	-2.544
30	20	370.829	373.385	-2.556
30	21	362.236	364.830	-2.594
30	24	372.056	374.607	-2.551
50	1	363.463	362.387	1.076
50	5	362.233	361.160	1.073
50	7	359.777	361.160	-1.383
50	11	368.375	369.750	-1.375
50	15	373.283	373.431	-0.148
50	20	370.829	370.977	-0.148
50	21	362.236	362.387	-0.151
50	24	372.056	372.204	-0.148
100	3	362.239	363.706	-1.467
100	8	367.145	367.363	-0.218
100	12	370.828	373.473	-2.645
100	13	373.284	374.697	-1.413
100	16	375.737	375.916	-0.179
100	17	362.235	364.918	-2.683
100	18	367.146	367.365	-0.219
100	19	365.919	368.588	-2.669
	Max	375.737	375.916	1.376
	Average	366.915	367.803	-0.888
	Min	359.777	359.629	-3.820
	Std Dev	4.925	5.060	1.556



	VODH_30(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	430	mV
Min Limit	320	mV

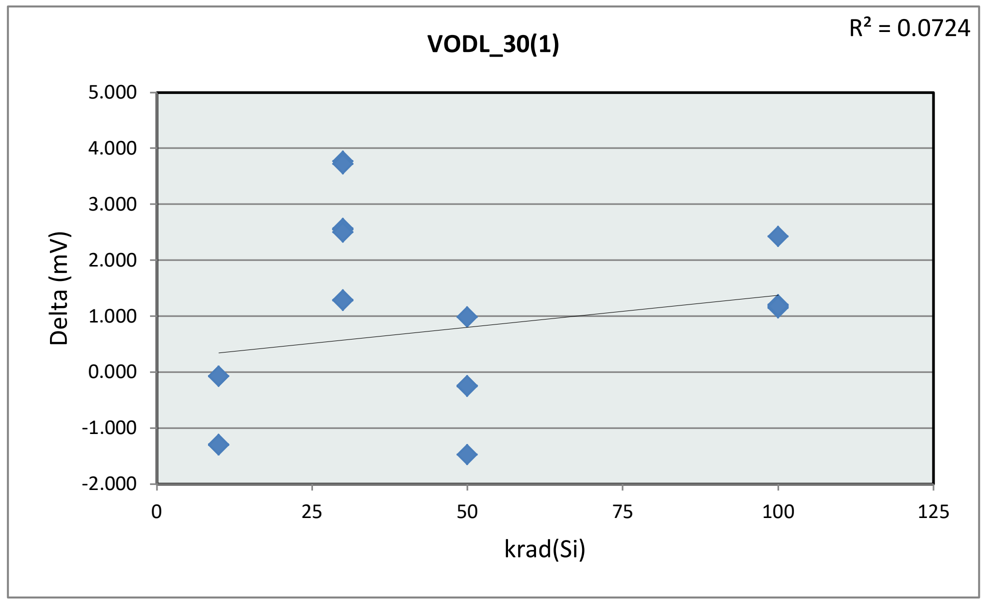
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	359.629	363.597	361.160	363.706
Average	365.770	369.258	366.682	369.503
Max	373.133	375.827	373.431	375.916
UL	430.000	430.000	430.000	430.000



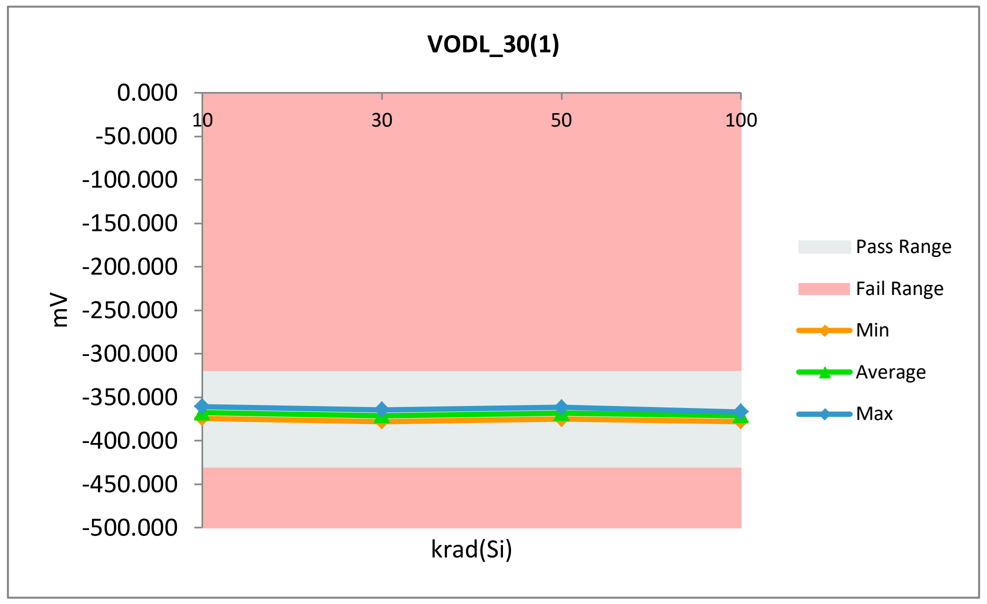
LDR Biased TID Report
SN55LVCP22A-SP

	VODL_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-364.338	-364.266	-0.072
10	5	-365.567	-364.269	-1.298
10	7	-361.887	-360.590	-1.297
10	11	-370.471	-369.168	-1.303
10	15	-374.155	-374.079	-0.076
10	20	-372.927	-371.624	-1.303
10	21	-364.337	-364.264	-0.073
10	24	-374.154	-374.078	-0.076
30	1	-364.338	-366.883	2.545
30	5	-365.567	-368.111	2.544
30	7	-361.887	-364.449	2.562
30	11	-370.471	-371.760	1.289
30	15	-374.155	-375.429	1.274
30	20	-372.927	-375.429	2.502
30	21	-364.337	-368.103	3.766
30	24	-374.154	-377.870	3.716
50	1	-364.338	-364.087	-0.251
50	5	-365.567	-364.087	-1.480
50	7	-361.887	-361.633	-0.254
50	11	-370.471	-370.223	-0.248
50	15	-374.155	-373.905	-0.250
50	20	-372.927	-372.677	-0.250
50	21	-364.337	-365.315	0.978
50	24	-374.154	-375.132	0.978
100	3	-364.334	-366.759	2.425
100	8	-366.793	-367.988	1.195
100	12	-372.928	-374.093	1.165
100	13	-376.609	-377.755	1.146
100	16	-375.382	-376.536	1.154
100	17	-365.566	-366.768	1.202
100	18	-366.792	-367.985	1.193
100	19	-370.473	-371.649	1.176
	Max	-361.887	-360.590	3.766
	Average	-368.825	-369.593	0.768
	Min	-376.609	-377.870	-1.480
	Std Dev	4.712	4.926	1.447



	VODL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-374.079	-377.870	-375.132	-377.755
Average	-367.792	-371.004	-368.382	-371.192
Max	-360.590	-364.449	-361.633	-366.759
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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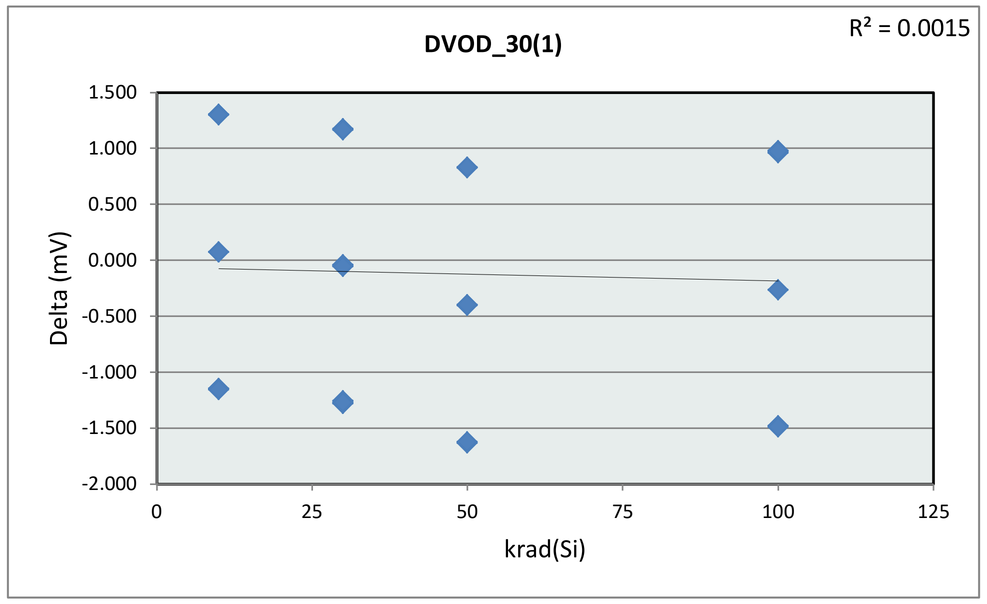
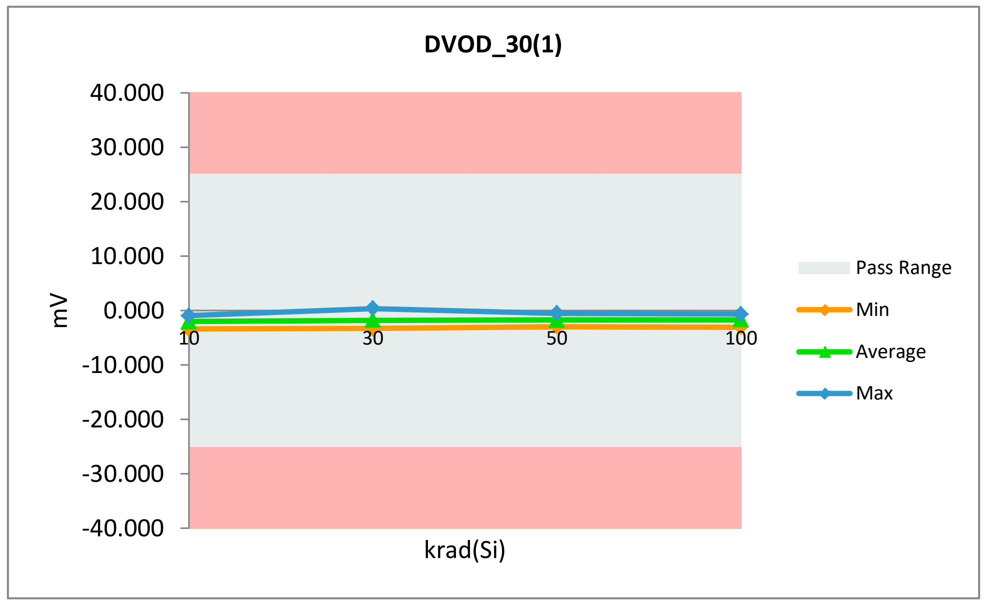
		DVOD_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.875	-2.178	1.302
10	5	-3.334	-2.184	-1.150
10	7	-2.109	-0.960	-1.149
10	11	-2.096	-0.940	-1.156
10	15	-0.873	-0.946	0.073
10	20	-2.098	-2.170	0.072
10	21	-2.101	-3.402	1.301
10	24	-2.098	-3.398	1.299
30	1	-0.875	-0.834	-0.042
30	5	-3.334	-3.288	-0.046
30	7	-2.109	-0.852	-1.258
30	11	-2.096	-0.815	-1.281
30	15	-0.873	0.397	-1.270
30	20	-2.098	-2.043	-0.055
30	21	-2.101	-3.273	1.172
30	24	-2.098	-3.263	1.165
50	1	-0.875	-1.701	0.825
50	5	-3.334	-2.928	-0.406
50	7	-2.109	-0.473	-1.636
50	11	-2.096	-0.473	-1.623
50	15	-0.873	-0.473	-0.399
50	20	-2.098	-1.700	-0.398
50	21	-2.101	-2.928	0.826
50	24	-2.098	-2.927	0.829
100	3	-2.095	-3.054	0.959
100	8	0.352	-0.626	0.978
100	12	-2.100	-0.621	-1.479
100	13	-3.326	-3.058	-0.268
100	16	0.355	-0.619	0.975
100	17	-3.332	-1.850	-1.482
100	18	0.354	-0.620	0.974
100	19	-4.553	-3.061	-1.492
	Max	0.355	0.397	1.302
	Average	-1.909	-1.789	-0.120
	Min	-4.553	-3.402	-1.636
	Std Dev	1.129	1.155	1.055



	DVOD_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-3.402	-3.288	-2.928	-3.061
Average	-2.022	-1.746	-1.701	-1.689
Max	-0.940	0.397	-0.473	-0.619
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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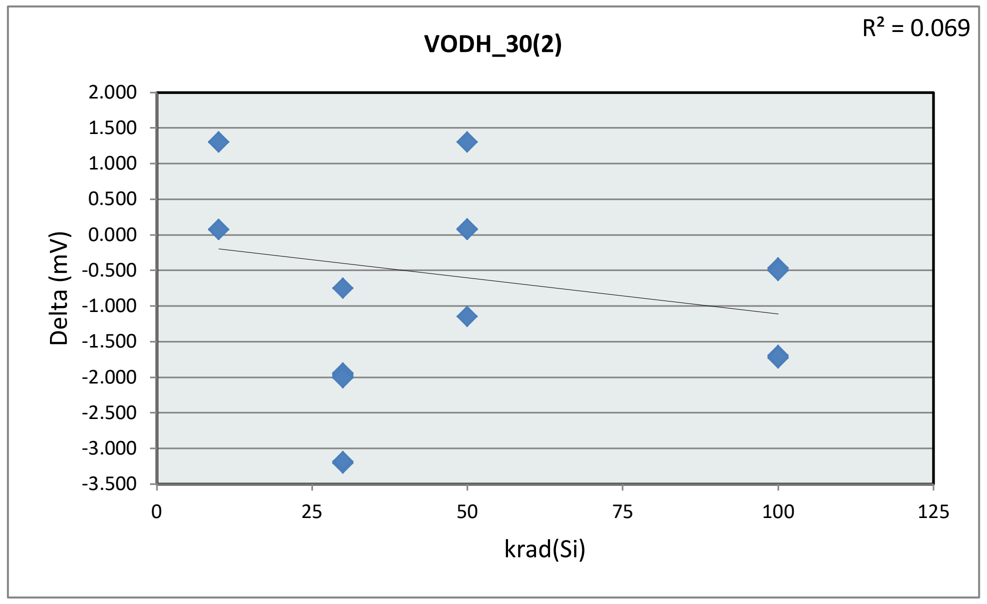
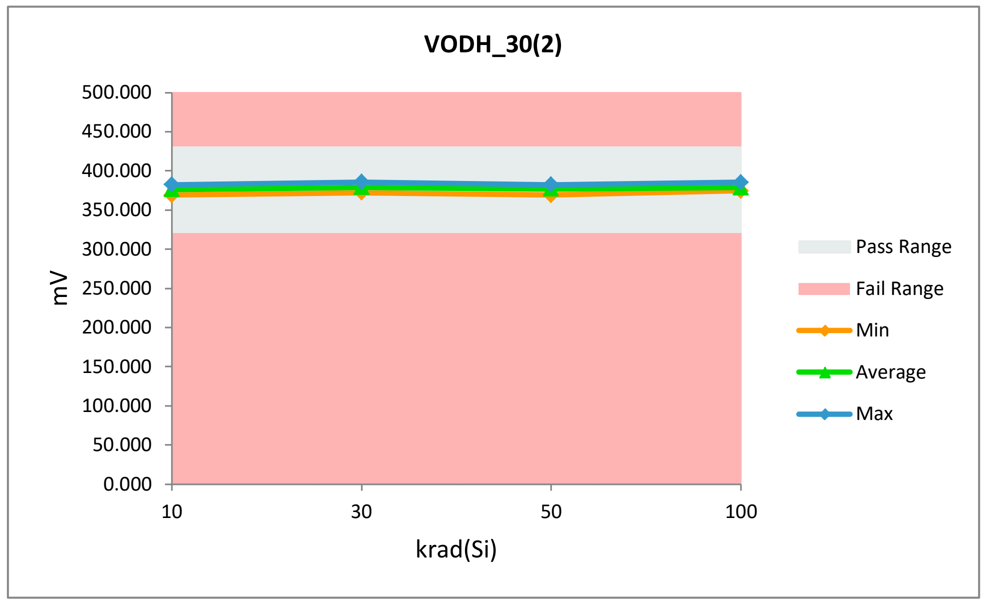
		VODH_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	376.377	375.079	1.298
10	5	370.236	370.167	0.069
10	7	372.695	371.397	1.298
10	11	380.065	379.992	0.073
10	15	381.286	379.988	1.298
10	20	382.518	382.446	0.072
10	21	370.241	368.943	1.298
10	24	382.522	382.448	0.074
30	1	376.377	377.126	-0.749
30	5	370.236	373.449	-3.213
30	7	372.695	374.690	-1.995
30	11	380.065	382.035	-1.970
30	15	381.286	383.232	-1.946
30	20	382.518	384.473	-1.955
30	21	370.241	372.249	-2.008
30	24	382.522	385.710	-3.188
50	1	376.377	376.302	0.075
50	5	370.236	370.162	0.074
50	7	372.695	371.393	1.302
50	11	380.065	379.987	0.078
50	15	381.286	382.438	-1.152
50	20	382.518	382.441	0.077
50	21	370.241	368.938	1.303
50	24	382.522	382.443	0.079
100	3	372.695	374.431	-1.736
100	8	377.606	378.094	-0.488
100	12	377.609	379.334	-1.725
100	13	384.973	385.439	-0.466
100	16	381.289	381.762	-0.473
100	17	373.921	374.423	-0.502
100	18	376.378	378.077	-1.699
100	19	375.149	376.871	-1.722
	Max	384.973	385.710	1.303
	Average	377.108	377.686	-0.579
	Min	370.236	368.938	-3.213
	Std Dev	4.790	5.085	1.321



	VODH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	368.943	372.249	368.938	374.423
Average	376.308	379.121	376.763	378.554
Max	382.448	385.710	382.443	385.439
UL	430.000	430.000	430.000	430.000



LDR Biased TID Report
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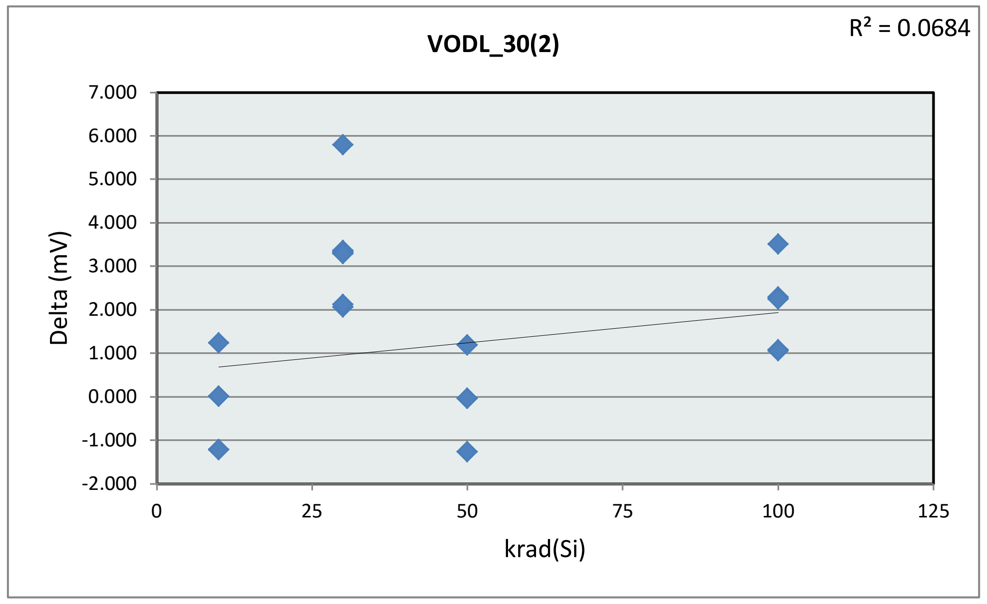
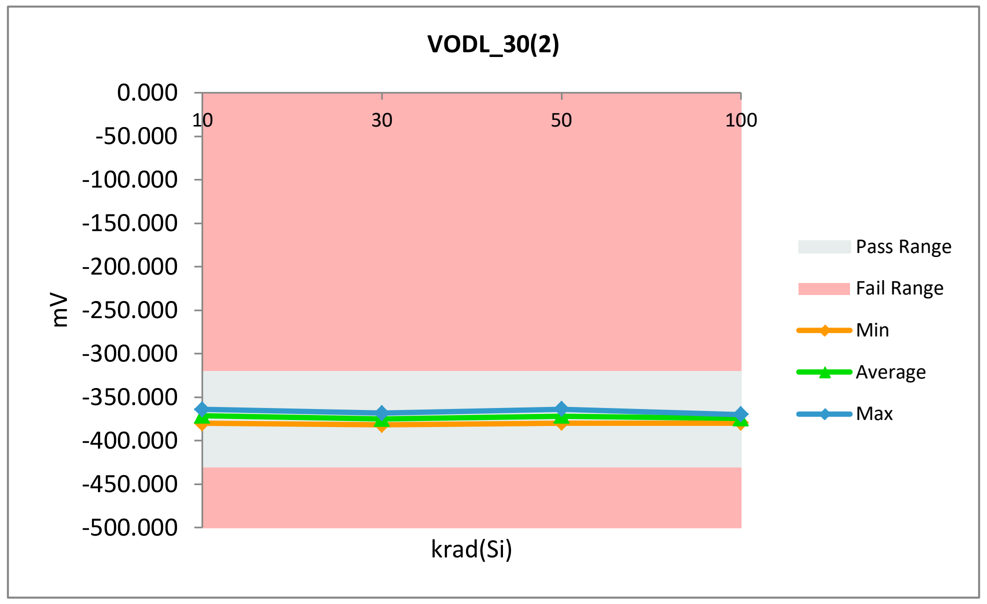
	VODL_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-368.805	-370.043	1.238
10	5	-365.125	-363.906	-1.219
10	7	-367.575	-367.586	0.011
10	11	-374.938	-373.722	-1.216
10	15	-376.172	-376.181	0.009
10	20	-379.850	-379.861	0.011
10	21	-366.346	-365.130	-1.216
10	24	-376.164	-374.949	-1.215
30	1	-368.805	-374.592	5.787
30	5	-365.125	-368.491	3.366
30	7	-367.575	-370.915	3.340
30	11	-374.938	-378.239	3.301
30	15	-376.172	-379.485	3.313
30	20	-379.850	-381.912	2.062
30	21	-366.346	-368.469	2.123
30	24	-376.164	-379.455	3.291
50	1	-368.805	-369.995	1.190
50	5	-365.125	-363.860	-1.265
50	7	-367.575	-367.539	-0.036
50	11	-374.938	-376.129	1.191
50	15	-376.172	-376.133	-0.039
50	20	-379.850	-379.812	-0.038
50	21	-366.346	-365.083	-1.263
50	24	-376.164	-376.129	-0.035
100	3	-367.576	-369.875	2.299
100	8	-373.714	-374.765	1.051
100	12	-370.028	-372.302	2.274
100	13	-377.395	-379.645	2.250
100	16	-377.397	-379.654	2.257
100	17	-368.805	-369.880	1.075
100	18	-374.941	-376.003	1.062
100	19	-370.032	-373.546	3.514
	Max	-365.125	-363.860	5.787
	Average	-372.025	-373.228	1.202
	Min	-379.850	-381.912	-1.265
	Std Dev	4.917	5.275	1.805



	VODL_30(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-379.861	-381.912	-379.812	-379.654
Average	-371.422	-375.195	-371.835	-374.459
Max	-363.906	-368.469	-363.860	-369.875
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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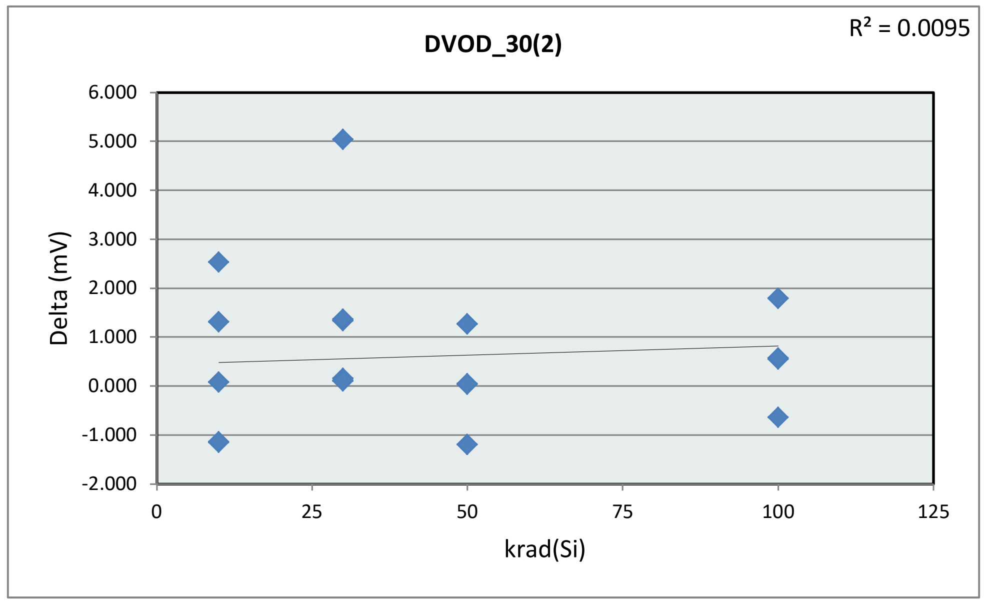
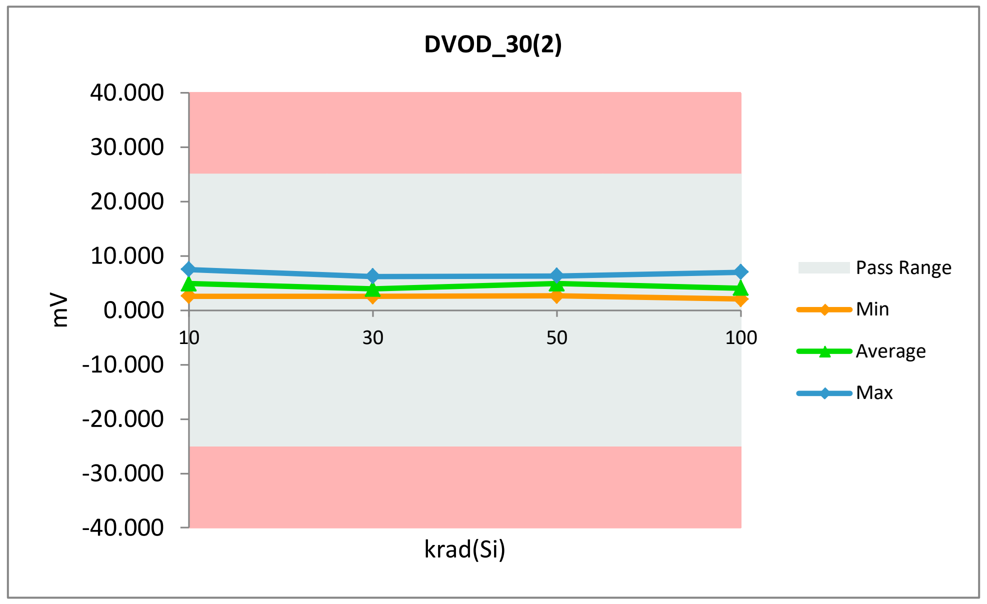
	DVOD_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	7.572	5.036	2.535
10	5	5.111	6.260	-1.149
10	7	5.120	3.811	1.309
10	11	5.127	6.270	-1.143
10	15	5.114	3.807	1.307
10	20	2.668	2.585	0.083
10	21	3.895	3.812	0.083
10	24	6.357	7.499	-1.142
30	1	7.572	2.534	5.038
30	5	5.111	4.958	0.153
30	7	5.120	3.775	1.345
30	11	5.127	3.796	1.331
30	15	5.114	3.747	1.367
30	20	2.668	2.562	0.106
30	21	3.895	3.780	0.115
30	24	6.357	6.254	0.103
50	1	7.572	6.307	1.265
50	5	5.111	6.303	-1.192
50	7	5.120	3.854	1.266
50	11	5.127	3.858	1.269
50	15	5.114	6.305	-1.192
50	20	2.668	2.628	0.040
50	21	3.895	3.855	0.040
50	24	6.357	6.314	0.043
100	3	5.120	4.556	0.564
100	8	3.892	3.329	0.563
100	12	7.581	7.032	0.549
100	13	7.578	5.794	1.784
100	16	3.892	2.108	1.784
100	17	5.117	4.543	0.574
100	18	1.437	2.074	-0.637
100	19	5.117	3.325	1.792
	Max	7.581	7.499	5.038
	Average	5.082	4.459	0.623
	Min	1.437	2.074	-1.192
	Std Dev	1.543	1.543	1.284



	DVOD_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.585	2.534	2.628	2.074
Average	4.885	3.926	4.928	4.095
Max	7.499	6.254	6.314	7.032
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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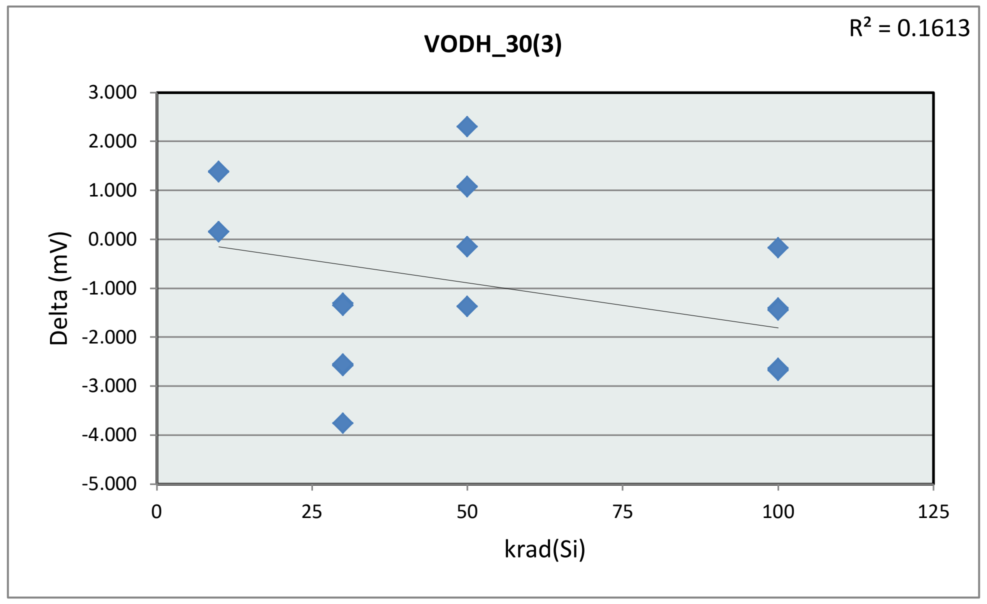
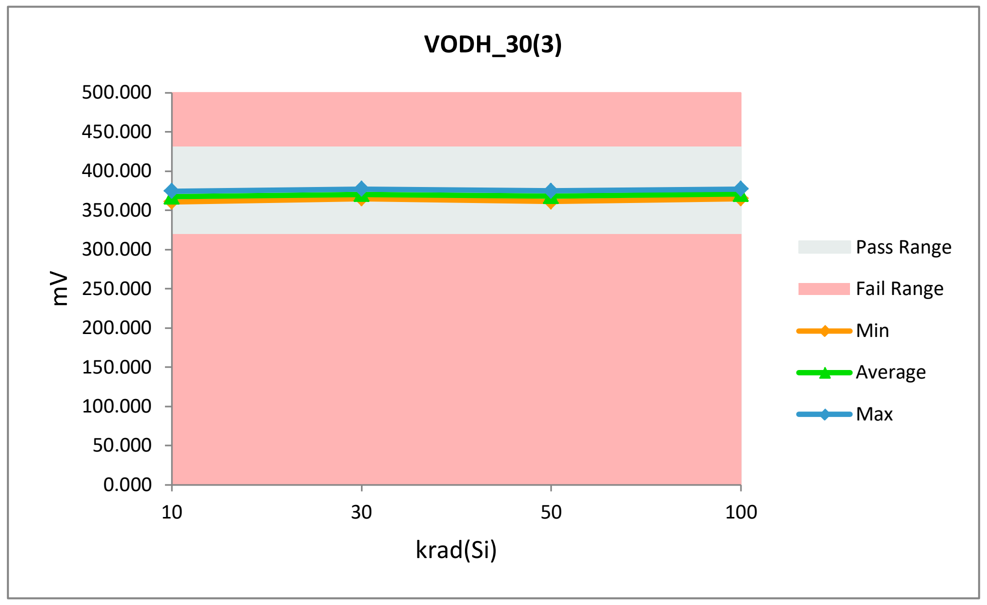
		VODH_30(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	363.461	363.312	0.149
10	5	364.686	363.309	1.377
10	7	362.230	360.853	1.377
10	11	369.600	369.452	0.148
10	15	374.508	374.357	0.151
10	20	370.827	370.677	0.150
10	21	364.689	363.313	1.376
10	24	373.281	373.131	0.150
30	1	363.461	366.044	-2.583
30	5	364.686	366.039	-1.353
30	7	362.230	364.813	-2.583
30	11	369.600	372.162	-2.562
30	15	374.508	375.821	-1.313
30	20	370.827	373.379	-2.552
30	21	364.689	366.046	-1.357
30	24	373.281	377.044	-3.763
50	1	363.461	363.614	-0.153
50	5	364.686	362.387	2.299
50	7	362.230	361.160	1.070
50	11	369.600	369.750	-0.150
50	15	374.508	374.658	-0.150
50	20	370.827	372.204	-1.377
50	21	364.689	363.614	1.075
50	24	373.281	374.658	-1.377
100	3	362.237	364.923	-2.686
100	8	367.142	368.580	-1.438
100	12	372.053	374.691	-2.638
100	13	374.509	375.915	-1.406
100	16	376.963	377.134	-0.171
100	17	363.460	364.915	-1.455
100	18	365.917	368.583	-2.666
100	19	367.145	369.806	-2.661
	Max	376.963	377.134	2.299
	Average	368.102	368.948	-0.846
	Min	362.230	360.853	-3.763
	Std Dev	4.643	5.128	1.554



	VODH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	360.853	364.813	361.160	364.915
Average	367.301	370.169	367.756	370.568
Max	374.357	377.044	374.658	377.134
UL	430.000	430.000	430.000	430.000



LDR Biased TID Report
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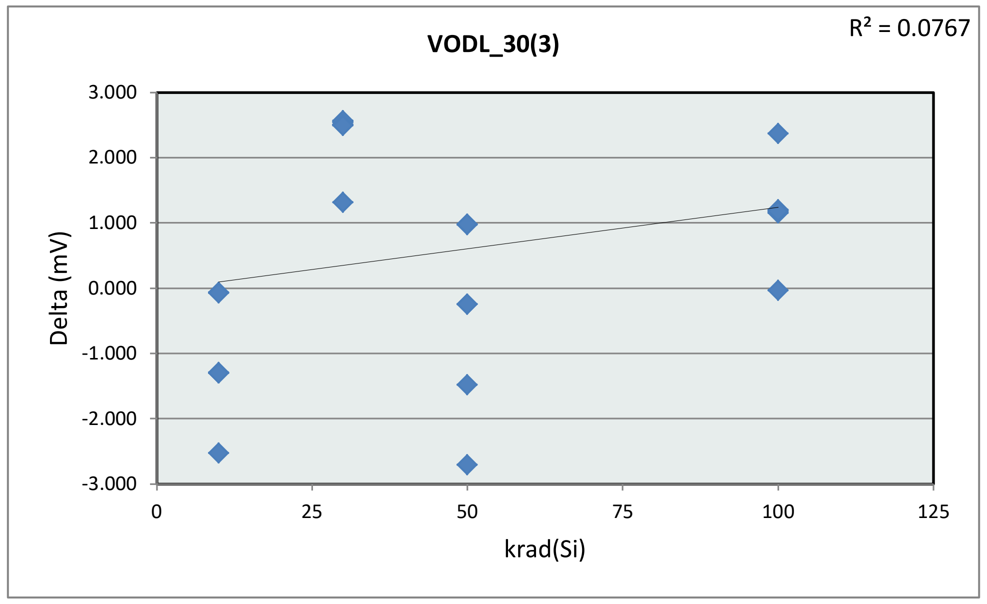
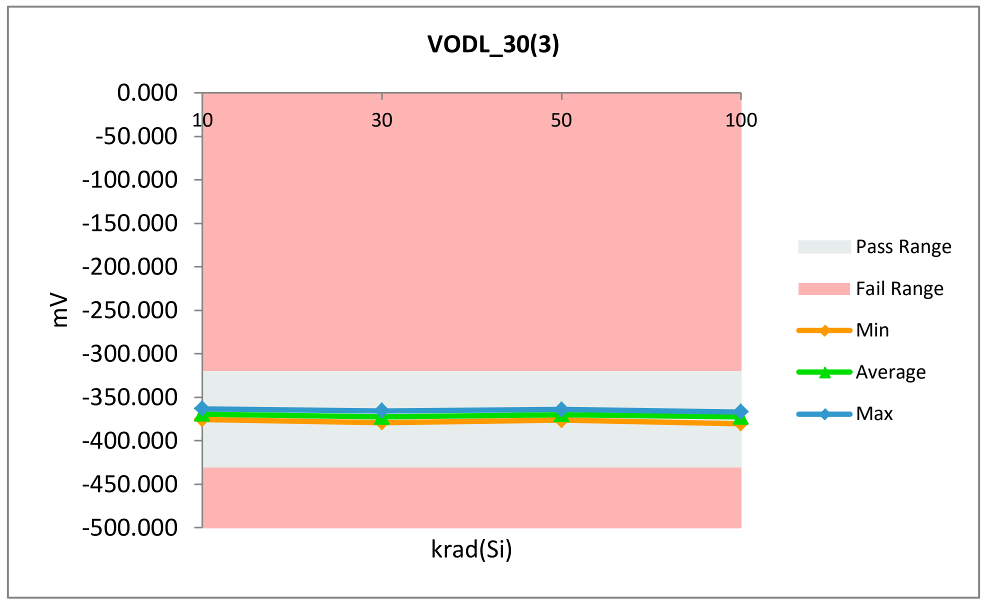
		VODL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-365.567	-365.496	-0.071
10	5	-366.797	-365.499	-1.298
10	7	-363.116	-363.046	-0.070
10	11	-371.701	-370.398	-1.303
10	15	-375.384	-375.308	-0.076
10	20	-374.157	-372.854	-1.303
10	21	-368.021	-365.494	-2.527
10	24	-376.611	-375.308	-1.303
30	1	-365.567	-368.111	2.544
30	5	-366.797	-369.338	2.541
30	7	-363.116	-365.676	2.560
30	11	-371.701	-374.209	2.508
30	15	-375.384	-377.878	2.494
30	20	-374.157	-376.655	2.498
30	21	-368.021	-369.330	1.309
30	24	-376.611	-379.098	2.487
50	1	-365.567	-366.542	0.975
50	5	-366.797	-365.315	-1.482
50	7	-363.116	-364.088	0.972
50	11	-371.701	-372.677	0.976
50	15	-375.384	-375.132	-0.252
50	20	-374.157	-373.905	-0.252
50	21	-368.021	-365.315	-2.706
50	24	-376.611	-376.359	-0.252
100	3	-365.564	-366.763	1.199
100	8	-369.250	-369.214	-0.036
100	12	-374.158	-375.318	1.160
100	13	-377.838	-380.202	2.364
100	16	-376.612	-377.761	1.149
100	17	-368.023	-369.215	1.192
100	18	-368.021	-369.210	1.189
100	19	-371.702	-372.874	1.172
	Max	-363.116	-363.046	2.560
	Average	-370.476	-371.050	0.574
	Min	-377.838	-380.202	-2.706
	Std Dev	4.643	4.957	1.558



	VODL_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-375.308	-379.098	-376.359	-380.202
Average	-369.175	-372.537	-369.917	-372.570
Max	-363.046	-365.676	-364.088	-366.763
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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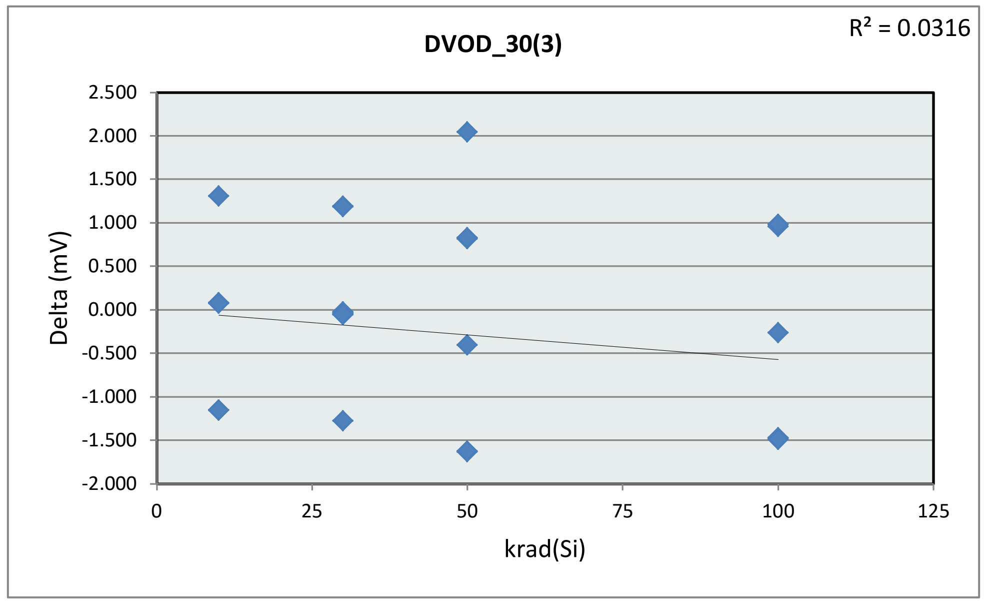
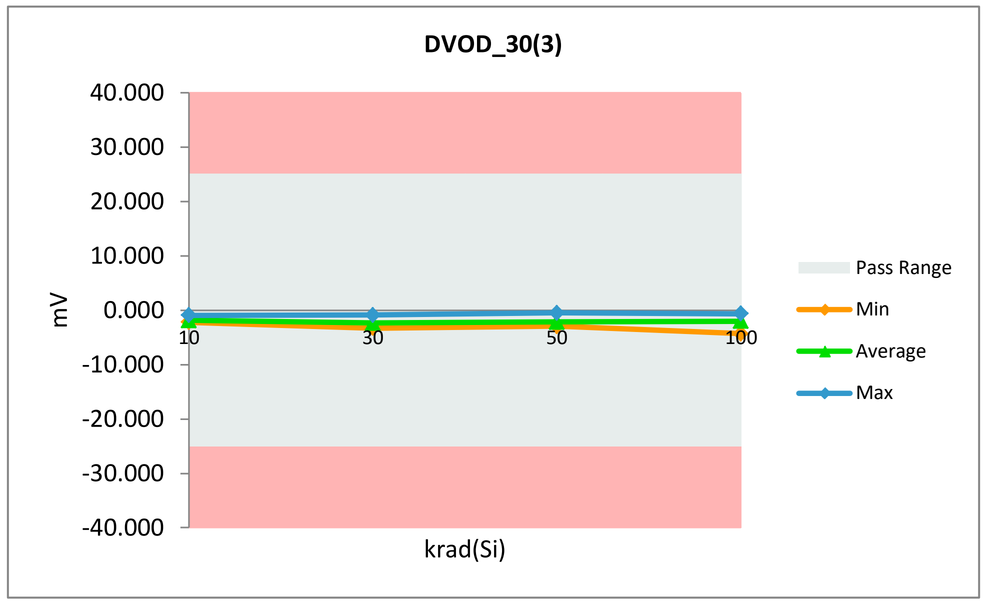
		DVOD_30(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-2.107	-2.184	0.077
10	5	-2.111	-2.190	0.079
10	7	-0.886	-2.193	1.307
10	11	-2.100	-0.946	-1.155
10	15	-0.876	-0.951	0.075
10	20	-3.330	-2.176	-1.153
10	21	-3.333	-2.181	-1.151
10	24	-3.330	-2.177	-1.153
30	1	-2.107	-2.067	-0.040
30	5	-2.111	-3.299	1.188
30	7	-0.886	-0.862	-0.023
30	11	-2.100	-2.047	-0.053
30	15	-0.876	-2.057	1.181
30	20	-3.330	-3.276	-0.054
30	21	-3.333	-3.284	-0.049
30	24	-3.330	-2.054	-1.276
50	1	-2.107	-2.928	0.821
50	5	-2.111	-2.928	0.817
50	7	-0.886	-2.928	2.043
50	11	-2.100	-2.928	0.827
50	15	-0.876	-0.473	-0.403
50	20	-3.330	-1.701	-1.629
50	21	-3.333	-1.701	-1.632
50	24	-3.330	-1.701	-1.630
100	3	-3.326	-1.839	-1.487
100	8	-2.107	-0.634	-1.473
100	12	-2.104	-0.628	-1.476
100	13	-3.329	-4.287	0.958
100	16	0.351	-0.628	0.979
100	17	-4.563	-4.300	-0.263
100	18	-2.104	-0.628	-1.476
100	19	-4.557	-3.068	-1.489
	Max	0.351	-0.473	2.043
	Average	-2.374	-2.101	-0.272
	Min	-4.563	-4.300	-1.632
	Std Dev	1.154	1.041	1.083



	DVOD_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-2.193	-3.299	-2.928	-4.300
Average	-1.875	-2.368	-2.161	-2.001
Max	-0.946	-0.862	-0.473	-0.628
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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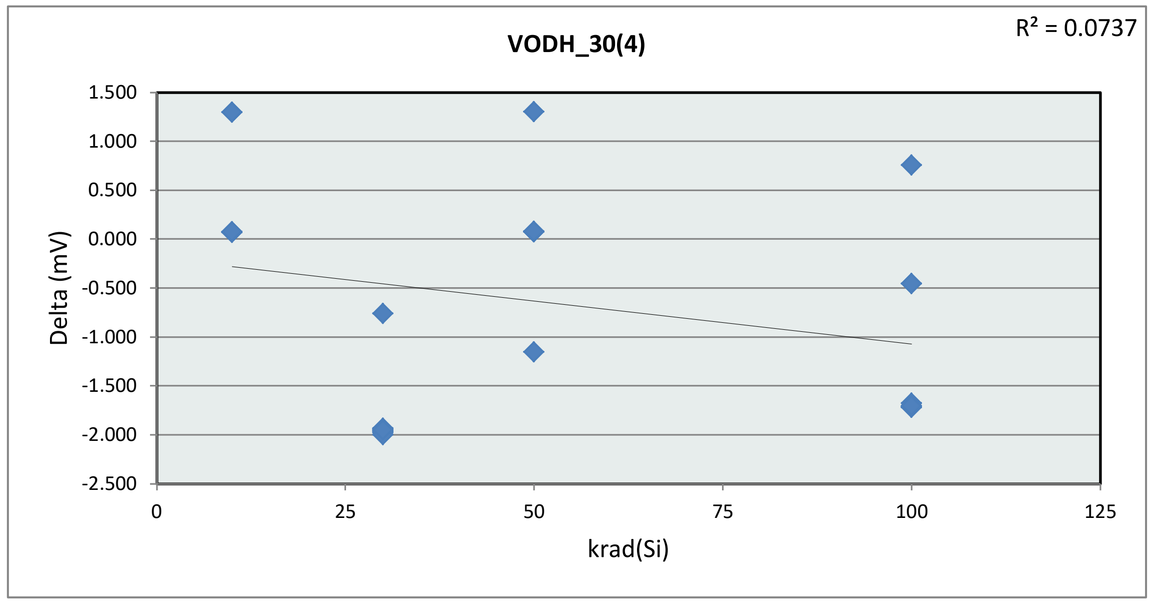
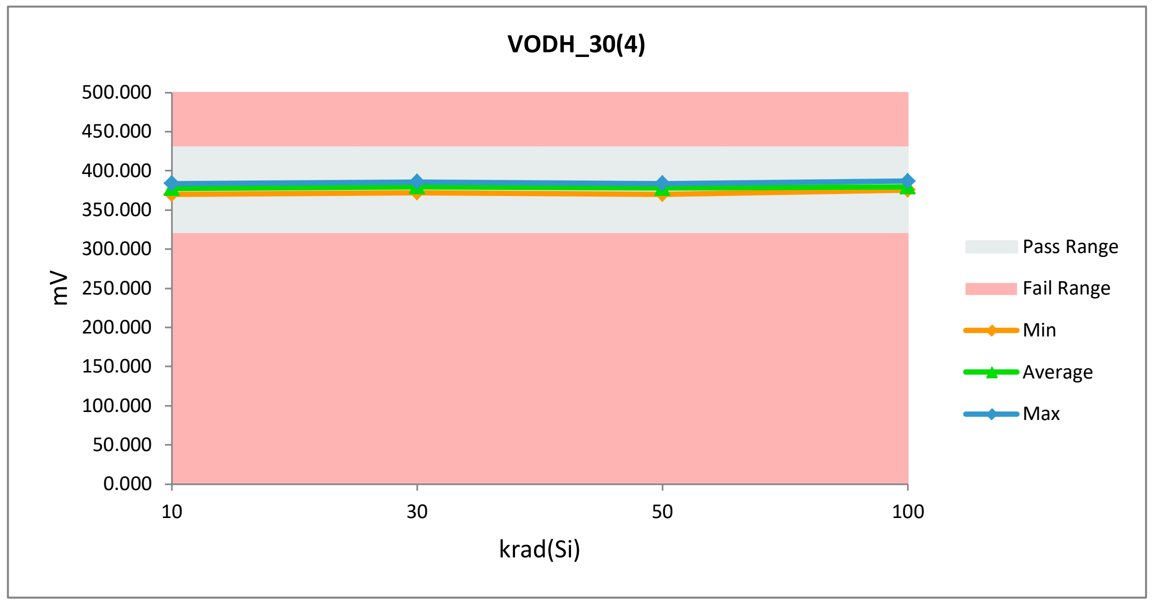
	VODH_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	376.374	376.305	0.069
10	5	371.461	371.393	0.068
10	7	373.921	372.623	1.298
10	11	381.289	381.218	0.071
10	15	382.511	381.214	1.297
10	20	383.743	383.672	0.071
10	21	370.239	370.169	0.070
10	24	383.746	383.674	0.072
30	1	376.374	378.338	-1.964
30	5	371.461	373.438	-1.977
30	7	373.921	374.680	-0.759
30	11	381.289	383.245	-1.956
30	15	382.511	384.444	-1.933
30	20	383.743	385.684	-1.941
30	21	370.239	372.239	-2.000
30	24	383.746	385.698	-1.952
50	1	376.374	377.527	-1.153
50	5	371.461	371.388	0.073
50	7	373.921	372.619	1.302
50	11	381.289	381.213	0.076
50	15	382.511	382.437	0.074
50	20	383.743	383.667	0.076
50	21	370.239	370.165	0.074
50	24	383.746	383.669	0.077
100	3	373.920	375.641	-1.721
100	8	380.058	379.304	0.754
100	12	377.606	379.323	-1.717
100	13	384.970	386.647	-1.677
100	16	382.514	382.972	-0.458
100	17	373.919	375.633	-1.714
100	18	378.831	379.287	-0.456
100	19	376.374	378.081	-1.707
	Max	384.970	386.647	1.302
	Average	378.064	378.675	-0.611
	Min	370.239	370.165	-2.000
	Std Dev	4.978	5.093	1.100

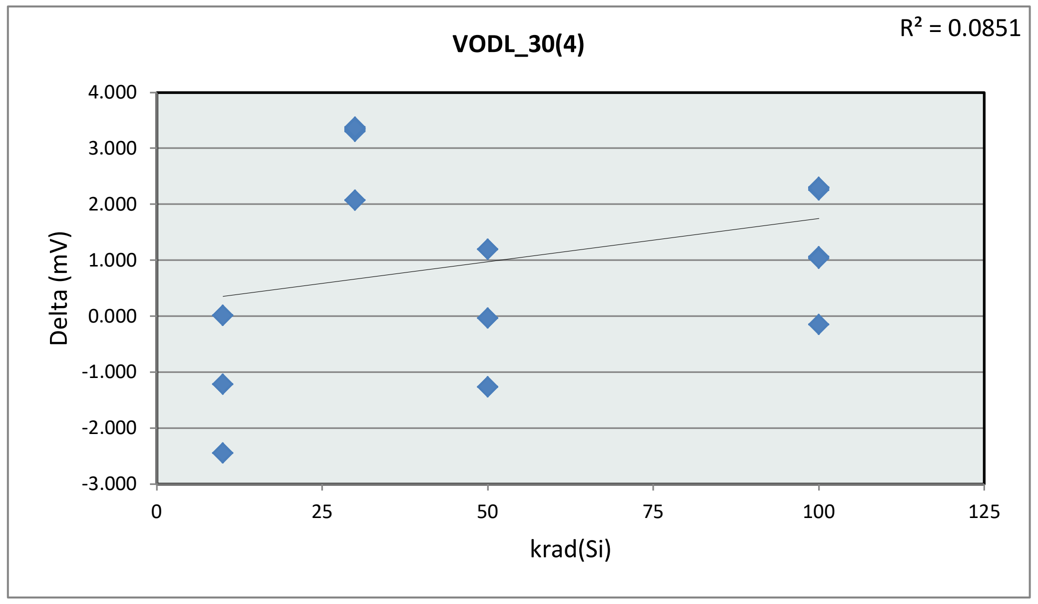


	VODH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	370.169	372.239	370.165	375.633
Average	377.534	379.721	377.836	379.611
Max	383.674	385.698	383.669	386.647
UL	430.000	430.000	430.000	430.000

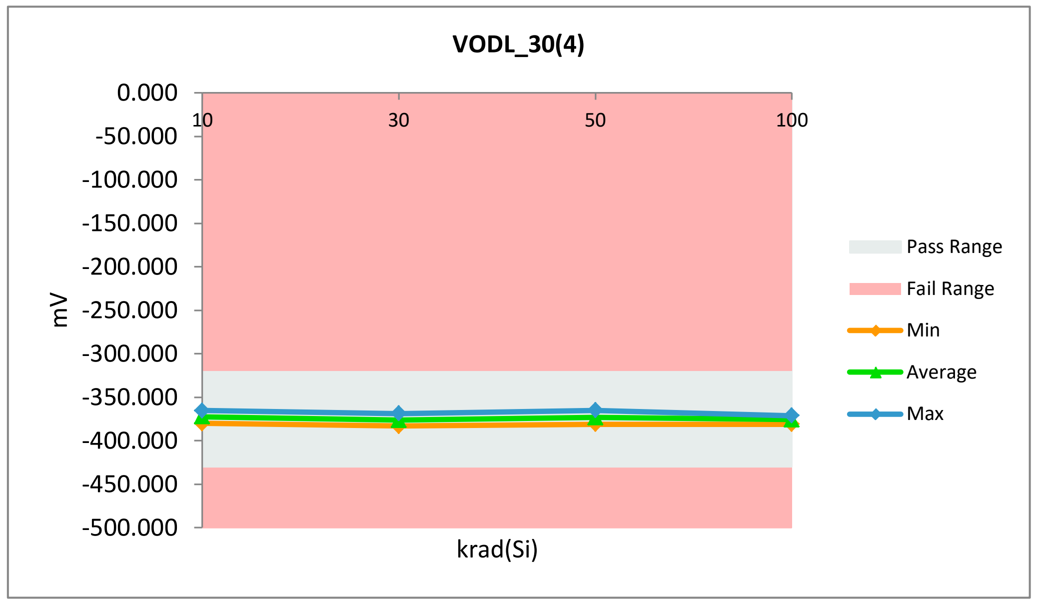


LDR Biased TID Report
SN55LVCP22A-SP

		VODL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-372.491	-370.044	-2.447
10	5	-365.127	-365.136	0.009
10	7	-368.805	-368.815	0.010
10	11	-376.168	-376.179	0.011
10	15	-377.402	-377.410	0.008
10	20	-381.081	-379.862	-1.219
10	21	-366.348	-365.132	-1.216
10	24	-378.623	-376.178	-2.445
30	1	-372.491	-375.825	3.334
30	5	-365.127	-368.501	3.374
30	7	-368.805	-372.148	3.343
30	11	-376.168	-379.472	3.304
30	15	-377.402	-380.719	3.317
30	20	-381.081	-383.146	2.065
30	21	-366.348	-369.700	3.352
30	24	-378.623	-380.689	2.066
50	1	-372.491	-371.224	-1.267
50	5	-365.127	-366.316	1.189
50	7	-368.805	-368.768	-0.037
50	11	-376.168	-377.358	1.190
50	15	-377.402	-378.590	1.188
50	20	-381.081	-381.042	-0.039
50	21	-366.348	-365.085	-1.263
50	24	-378.623	-377.357	-1.266
100	3	-368.806	-371.107	2.301
100	8	-374.945	-376.000	1.055
100	12	-371.258	-373.536	2.278
100	13	-378.626	-380.881	2.255
100	16	-379.855	-380.888	1.033
100	17	-370.034	-372.336	2.302
100	18	-376.171	-376.015	-0.156
100	19	-372.490	-374.780	2.290
	Max	-365.127	-365.085	3.374
	Average	-373.447	-374.382	0.935
	Min	-381.081	-383.146	-2.447
	Std Dev	5.289	5.362	1.793



	VODL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-379.862	-383.146	-381.042	-380.888
Average	-372.345	-376.275	-373.218	-375.693
Max	-365.132	-368.501	-365.085	-371.107
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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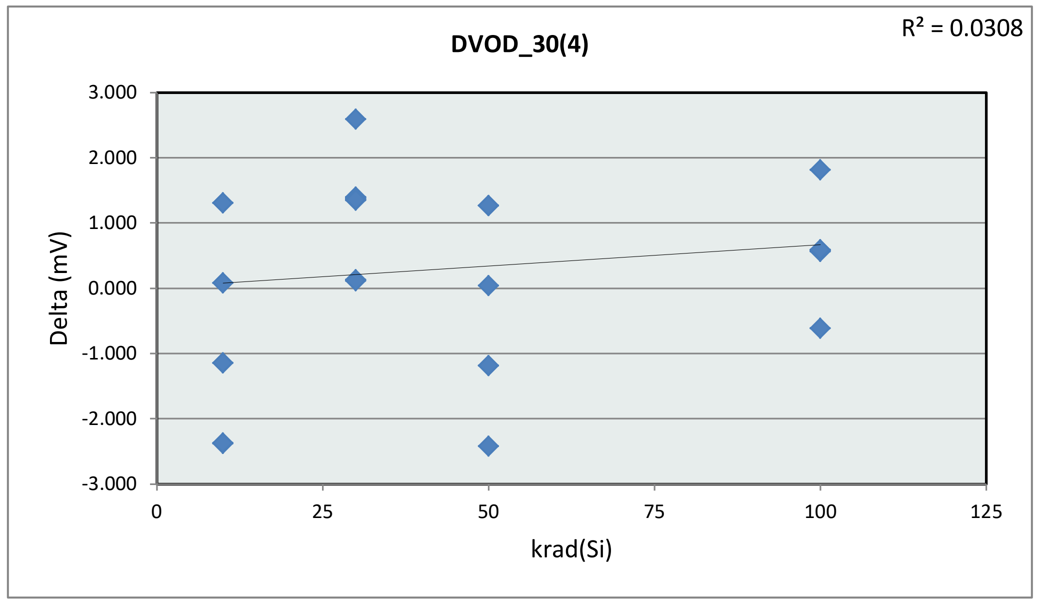
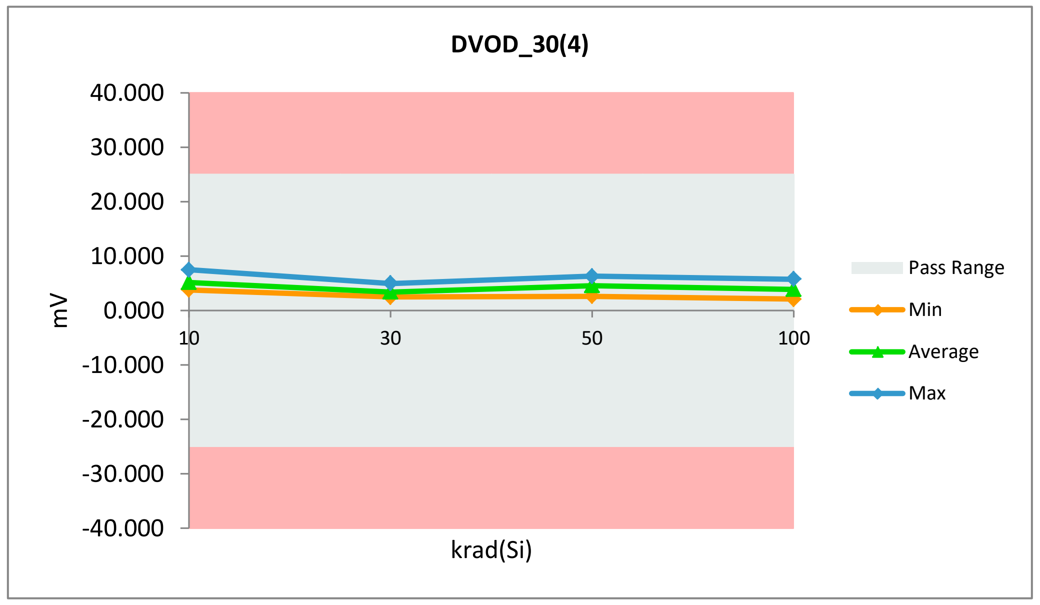
	DVOD_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.883	6.261	-2.378
10	5	6.333	6.257	0.076
10	7	5.116	3.809	1.307
10	11	5.121	5.039	0.082
10	15	5.108	3.804	1.305
10	20	2.662	3.809	-1.147
10	21	3.890	5.037	-1.146
10	24	5.124	7.496	-2.372
30	1	3.883	2.513	1.370
30	5	6.333	4.936	1.397
30	7	5.116	2.532	2.584
30	11	5.121	3.774	1.347
30	15	5.108	3.725	1.383
30	20	2.662	2.537	0.125
30	21	3.890	2.539	1.351
30	24	5.124	5.010	0.114
50	1	3.883	6.304	-2.420
50	5	6.333	5.073	1.261
50	7	5.116	3.852	1.264
50	11	5.121	3.855	1.266
50	15	5.108	3.847	1.261
50	20	2.662	2.625	0.037
50	21	3.890	5.080	-1.190
50	24	5.124	6.311	-1.188
100	3	5.115	4.533	0.582
100	8	5.113	3.305	1.808
100	12	6.349	5.786	0.563
100	13	6.344	5.766	0.578
100	16	2.659	2.083	0.576
100	17	3.884	3.297	0.587
100	18	2.660	3.273	-0.613
100	19	3.884	3.301	0.583
	Max	6.349	7.496	2.584
	Average	4.616	4.293	0.324
	Min	2.659	2.083	-2.420
	Std Dev	1.160	1.389	1.280



	DVOD_30(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.804	2.513	2.625	2.083
Average	5.189	3.446	4.618	3.918
Max	7.496	5.010	6.311	5.786
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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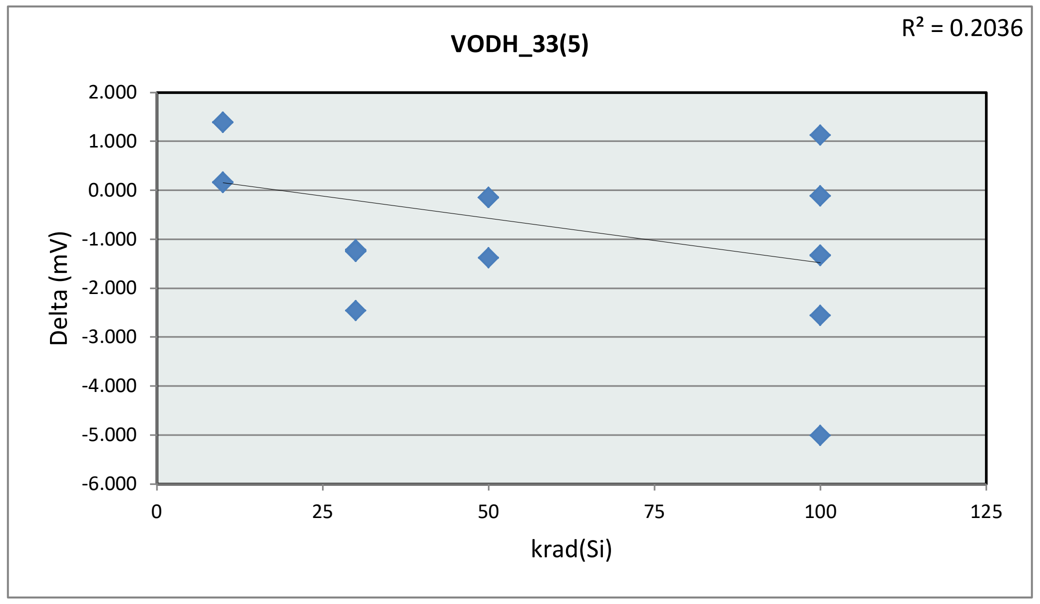
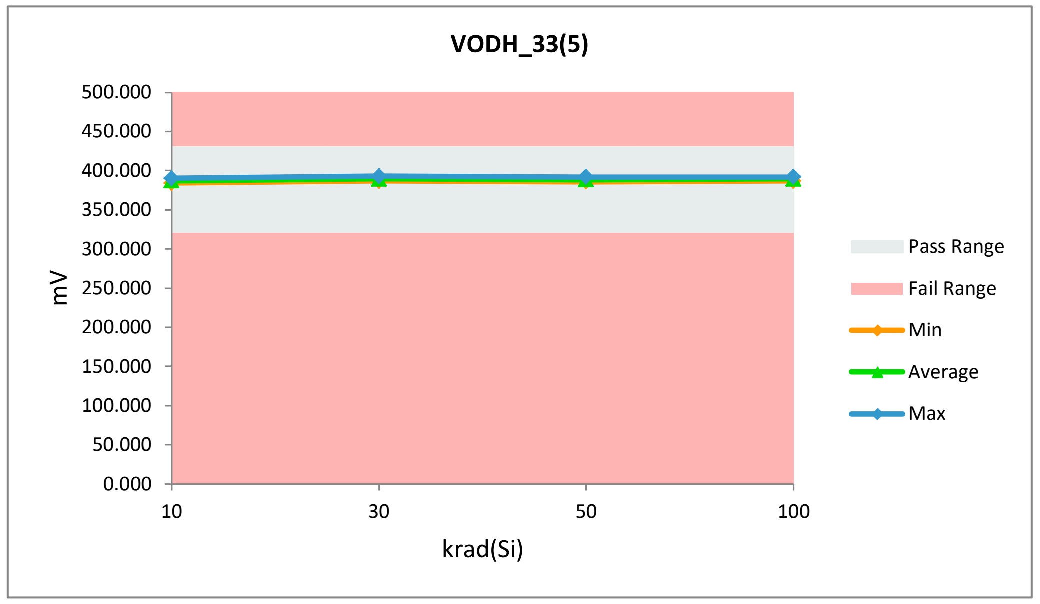
		VODH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	388.002	386.617	1.385
10	5	391.683	390.295	1.388
10	7	389.227	389.066	0.161
10	11	389.233	389.076	0.157
10	15	388.004	387.846	0.158
10	20	386.777	385.393	1.384
10	21	385.549	384.165	1.384
10	24	386.776	385.392	1.384
30	1	388.002	389.241	-1.239
30	5	391.683	392.901	-1.218
30	7	389.227	390.454	-1.227
30	11	389.233	390.471	-1.238
30	15	388.004	390.465	-2.461
30	20	386.777	388.024	-1.247
30	21	385.549	386.800	-1.251
30	24	386.776	388.023	-1.247
50	1	388.002	388.157	-0.155
50	5	391.683	391.838	-0.155
50	7	389.227	389.384	-0.157
50	11	389.233	389.384	-0.151
50	15	388.004	389.384	-1.380
50	20	386.777	386.930	-0.153
50	21	385.549	385.703	-0.154
50	24	386.776	386.930	-0.154
100	3	388.007	390.567	-2.560
100	8	386.774	386.893	-0.119
100	12	390.458	391.782	-1.324
100	13	388.004	389.340	-1.336
100	16	390.458	389.338	1.120
100	17	386.775	386.893	-0.118
100	18	386.777	391.783	-5.006
100	19	389.232	390.562	-1.330
	Max	391.683	392.901	1.388
	Average	388.195	388.722	-0.527
	Min	385.549	384.165	-5.006
	Std Dev	1.738	2.142	1.366



	VODH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	384.165	386.800	385.703	386.893
Average	387.231	389.547	388.464	389.645
Max	390.295	392.901	391.838	391.783
UL	430.000	430.000	430.000	430.000



LDR Biased TID Report
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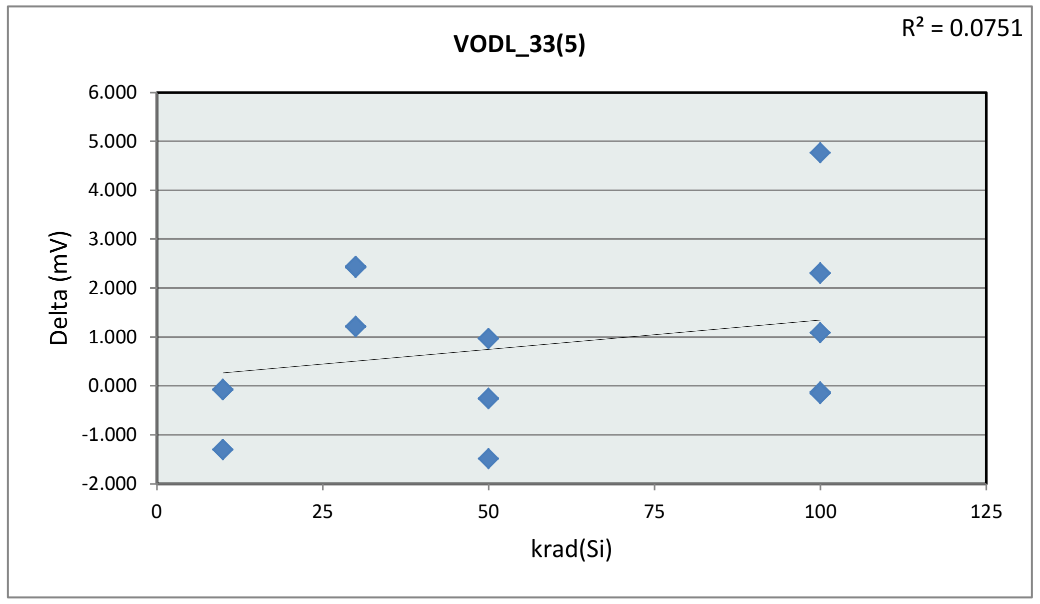
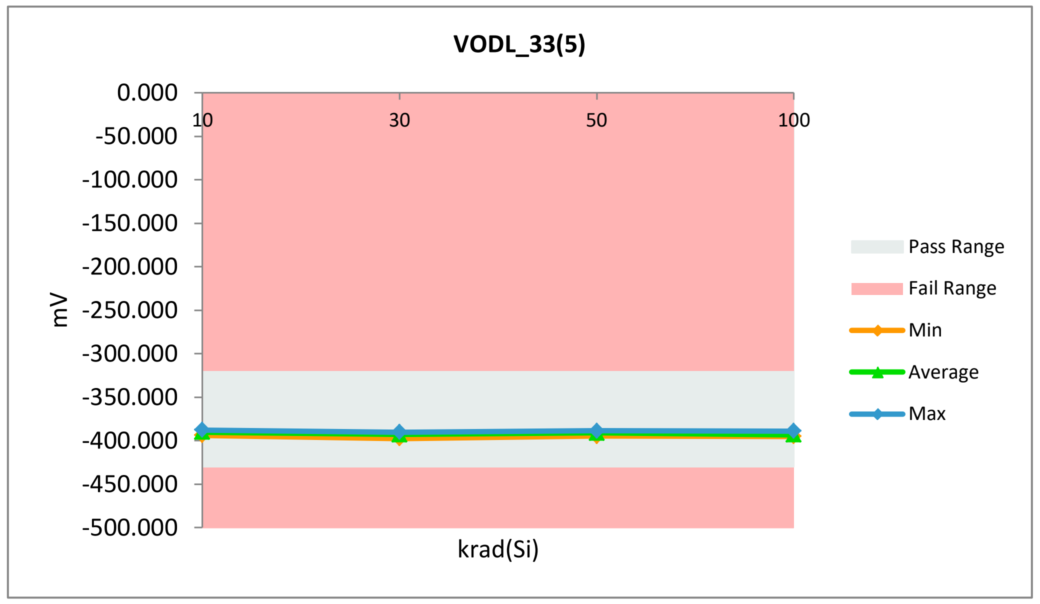
	VODL_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-390.118	-390.041	-0.077
10	5	-395.030	-393.726	-1.304
10	7	-391.348	-391.273	-0.075
10	11	-390.115	-390.037	-0.078
10	15	-388.890	-387.586	-1.304
10	20	-390.117	-390.039	-0.078
10	21	-388.890	-387.586	-1.304
10	24	-391.345	-390.040	-1.305
30	1	-390.118	-392.554	2.436
30	5	-395.030	-397.446	2.416
30	7	-391.348	-393.783	2.435
30	11	-390.115	-392.546	2.431
30	15	-388.890	-390.108	1.218
30	20	-390.117	-392.550	2.433
30	21	-388.890	-391.330	2.440
30	24	-391.345	-392.551	1.206
50	1	-390.118	-391.085	0.967
50	5	-395.030	-394.766	-0.264
50	7	-391.348	-389.858	-1.490
50	11	-390.115	-391.085	0.970
50	15	-388.890	-389.858	0.968
50	20	-390.117	-391.085	0.968
50	21	-388.890	-388.631	-0.259
50	24	-391.345	-391.085	-0.260
100	3	-391.342	-393.644	2.302
100	8	-388.892	-388.768	-0.124
100	12	-395.027	-394.873	-0.154
100	13	-392.572	-394.871	2.299
100	16	-391.345	-391.209	-0.136
100	17	-391.346	-392.432	1.086
100	18	-388.890	-393.649	4.759
100	19	-395.026	-394.871	-0.155
	Max	-388.890	-387.586	4.759
	Average	-391.000	-391.718	0.718
	Min	-395.030	-397.446	-1.490
	Std Dev	2.027	2.316	1.497



	VODL_33(5)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-393.726	-397.446	-394.766	-394.873
Average	-390.041	-392.859	-390.932	-393.040
Max	-387.586	-390.108	-388.631	-388.768
UL	-320.000	-320.000	-320.000	-320.000



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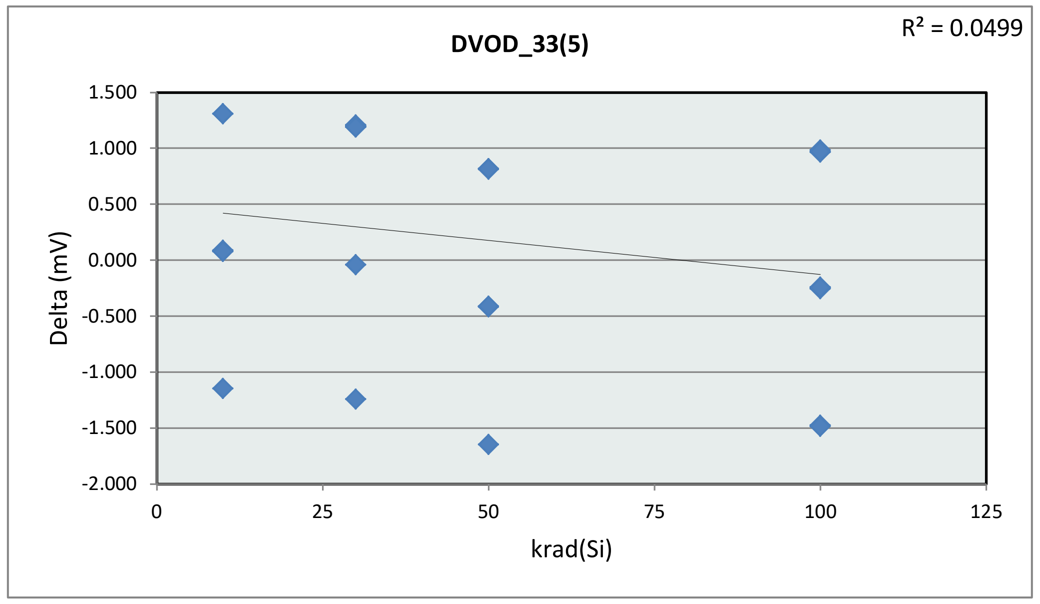
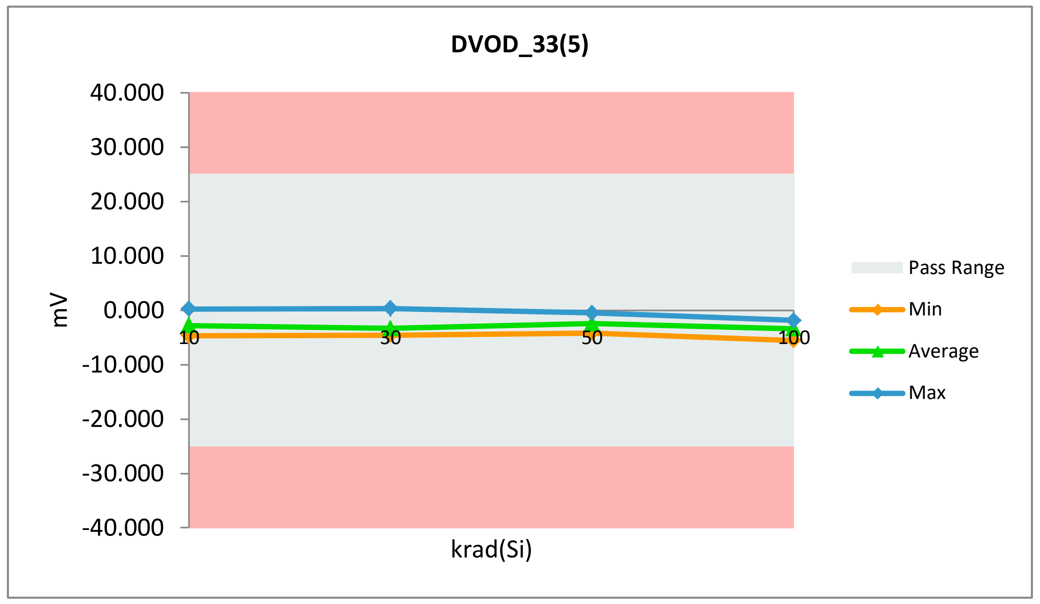
		DVOD_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-2.116	-3.424	1.308
10	5	-3.347	-3.431	0.084
10	7	-2.121	-2.206	0.085
10	11	-0.882	-0.961	0.078
10	15	-0.886	0.259	-1.146
10	20	-3.339	-4.646	1.306
10	21	-3.341	-3.422	0.081
10	24	-4.568	-4.647	0.079
30	1	-2.116	-3.314	1.198
30	5	-3.347	-4.545	1.198
30	7	-2.121	-3.329	1.208
30	11	-0.882	-2.075	1.193
30	15	-0.886	0.357	-1.243
30	20	-3.339	-4.526	1.187
30	21	-3.341	-4.530	1.189
30	24	-4.568	-4.528	-0.040
50	1	-2.116	-2.928	0.812
50	5	-3.347	-2.928	-0.419
50	7	-2.121	-0.474	-1.648
50	11	-0.882	-1.701	0.818
50	15	-0.886	-0.474	-0.413
50	20	-3.339	-4.155	0.816
50	21	-3.341	-2.928	-0.413
50	24	-4.568	-4.155	-0.413
100	3	-3.335	-3.077	-0.258
100	8	-2.118	-1.875	-0.243
100	12	-4.569	-3.091	-1.478
100	13	-4.567	-5.530	0.963
100	16	-0.888	-1.870	0.982
100	17	-4.572	-5.538	0.966
100	18	-2.113	-1.866	-0.247
100	19	-5.794	-4.308	-1.486
	Max	-0.882	0.357	1.308
	Average	-2.805	-2.996	0.191
	Min	-5.794	-5.538	-1.648
	Std Dev	1.392	1.593	0.925



	DVOD_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-4.647	-4.545	-4.155	-5.538
Average	-2.810	-3.311	-2.468	-3.394
Max	0.259	0.357	-0.474	-1.866
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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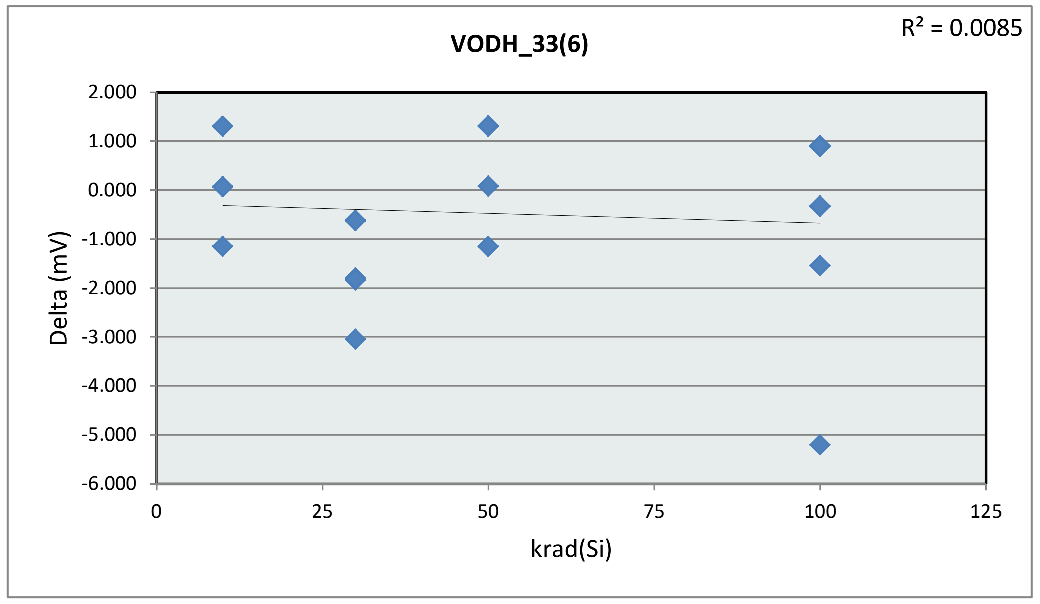
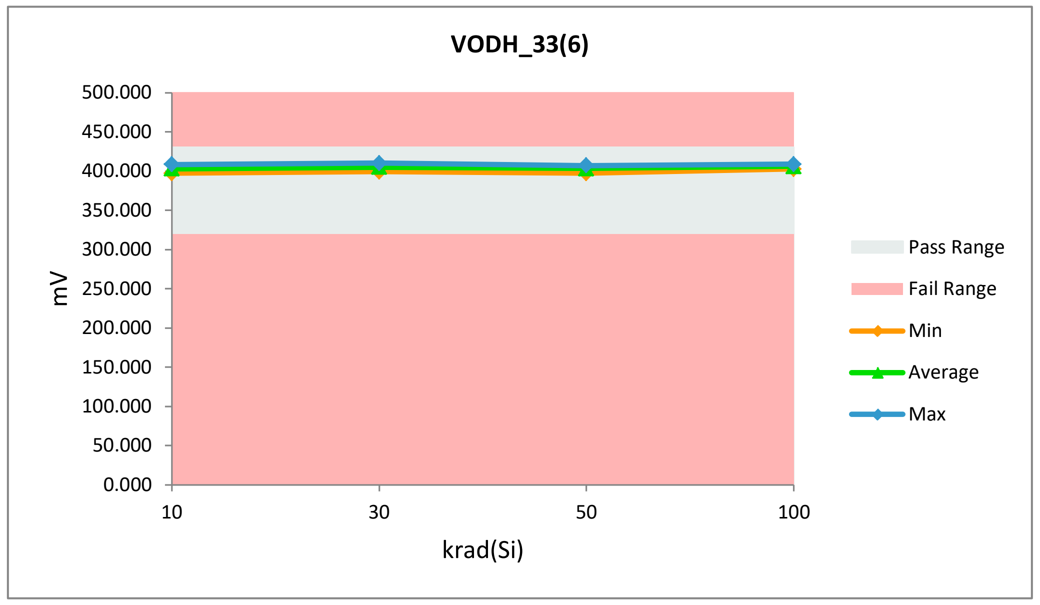
		VODH_33(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	403.375	404.534	-1.159
10	5	408.283	408.215	0.068
10	7	403.378	403.308	0.070
10	11	405.835	405.764	0.071
10	15	402.145	402.077	0.068
10	20	399.694	398.397	1.297
10	21	398.468	397.171	1.297
10	24	405.836	404.537	1.299
30	1	403.375	406.423	-3.048
30	5	408.283	410.079	-1.796
30	7	403.378	405.213	-1.835
30	11	405.835	407.662	-1.827
30	15	402.145	403.968	-1.823
30	20	399.694	400.317	-0.623
30	21	398.468	399.104	-0.636
30	24	405.836	407.667	-1.831
50	1	403.375	404.528	-1.153
50	5	408.283	406.981	1.302
50	7	403.378	402.074	1.304
50	11	405.835	406.985	-1.150
50	15	402.145	403.299	-1.154
50	20	399.694	399.619	0.075
50	21	398.468	397.165	1.303
50	24	405.836	405.758	0.078
100	3	408.288	407.385	0.903
100	8	403.375	402.489	0.886
100	12	405.835	406.177	-0.342
100	13	407.059	408.606	-1.547
100	16	404.604	403.712	0.892
100	17	403.376	403.712	-0.336
100	18	403.377	408.586	-5.209
100	19	407.058	407.380	-0.322
	Max	408.288	410.079	1.304
	Average	403.875	404.340	-0.465
	Min	398.468	397.165	-5.209
	Std Dev	2.988	3.465	1.476

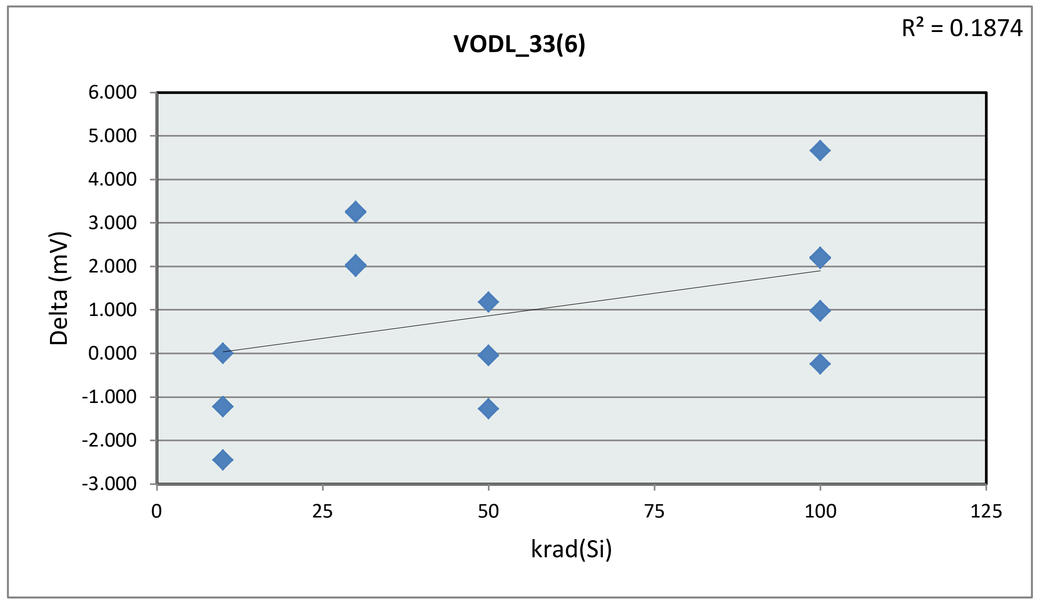


	VODH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	397.171	399.104	397.165	402.489
Average	403.000	405.054	403.301	406.006
Max	408.215	410.079	406.985	408.606
UL	430.000	430.000	430.000	430.000

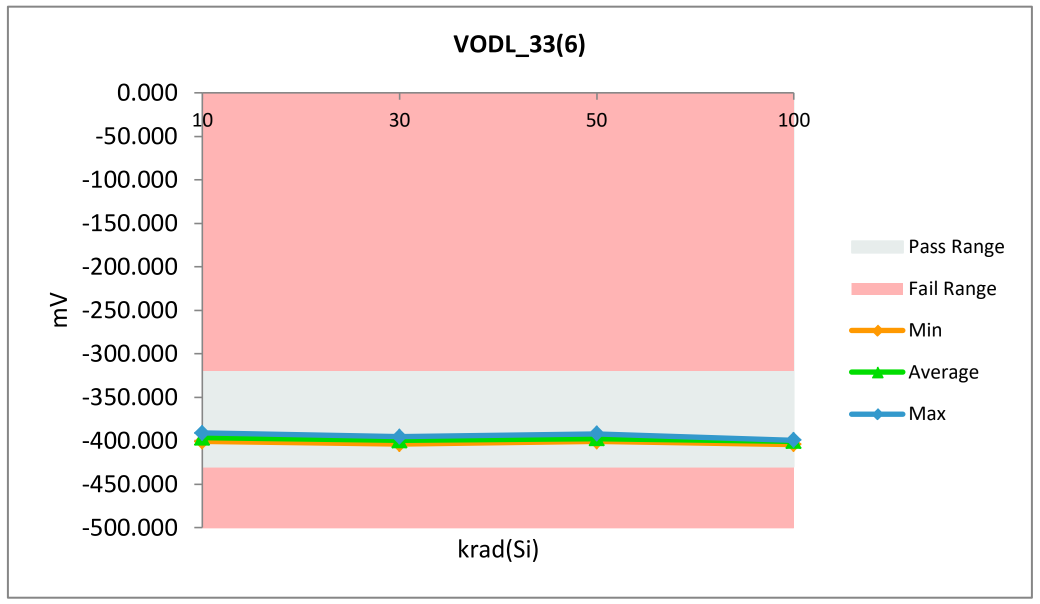


LDR Biased TID Report
SN55LVCP22A-SP

		VODL_33(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-398.278	-397.054	-1.224
10	5	-400.736	-400.738	0.002
10	7	-398.275	-397.052	-1.223
10	11	-399.501	-398.279	-1.222
10	15	-395.825	-395.828	0.003
10	20	-395.821	-395.826	0.005
10	21	-393.363	-390.914	-2.449
10	24	-397.045	-395.823	-1.222
30	1	-398.278	-400.299	2.021
30	5	-400.736	-403.975	3.239
30	7	-398.275	-400.285	2.010
30	11	-399.501	-401.503	2.002
30	15	-395.825	-399.084	3.259
30	20	-395.821	-397.848	2.027
30	21	-393.363	-395.393	2.030
30	24	-397.045	-399.055	2.010
50	1	-398.278	-398.232	-0.046
50	5	-400.736	-400.689	-0.047
50	7	-398.275	-398.230	-0.045
50	11	-399.501	-399.457	-0.044
50	15	-395.825	-395.779	-0.046
50	20	-395.821	-397.004	1.183
50	21	-393.363	-392.092	-1.271
50	24	-397.045	-397.002	-0.043
100	3	-399.504	-401.694	2.190
100	8	-398.278	-399.256	0.978
100	12	-397.045	-399.233	2.188
100	13	-398.277	-399.250	0.973
100	16	-399.505	-399.256	-0.249
100	17	-397.049	-399.254	2.205
100	18	-398.276	-402.936	4.660
100	19	-401.961	-404.144	2.183
	Max	-393.363	-390.914	4.660
	Average	-397.701	-398.515	0.814
	Min	-401.961	-404.144	-2.449
	Std Dev	2.161	2.939	1.629

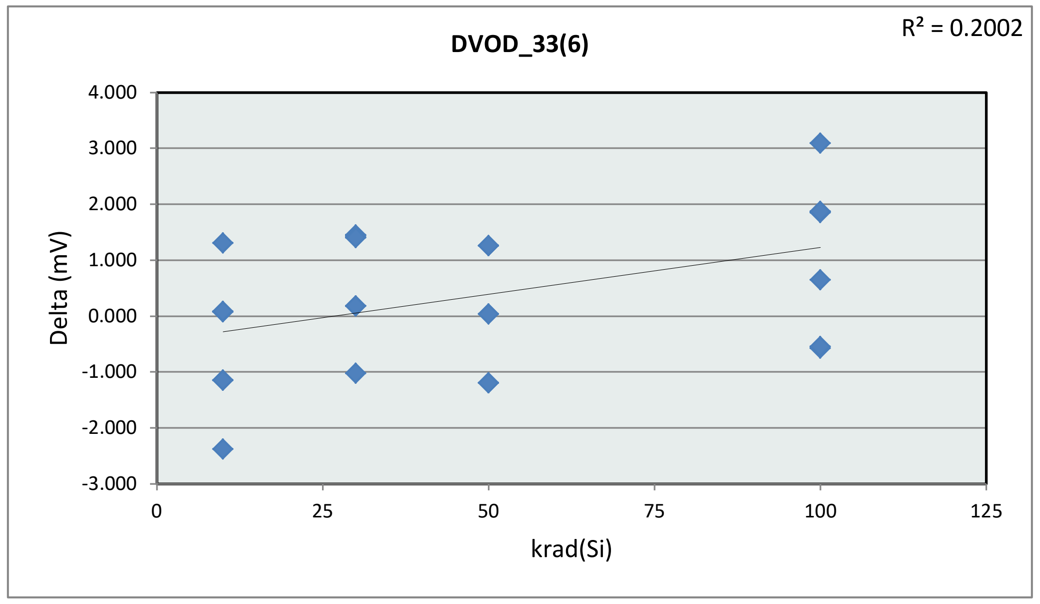


	VODL_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-400.738	-403.975	-400.689	-404.144
Average	-396.439	-399.680	-397.311	-400.628
Max	-390.914	-395.393	-392.092	-399.233
UL	-320.000	-320.000	-320.000	-320.000

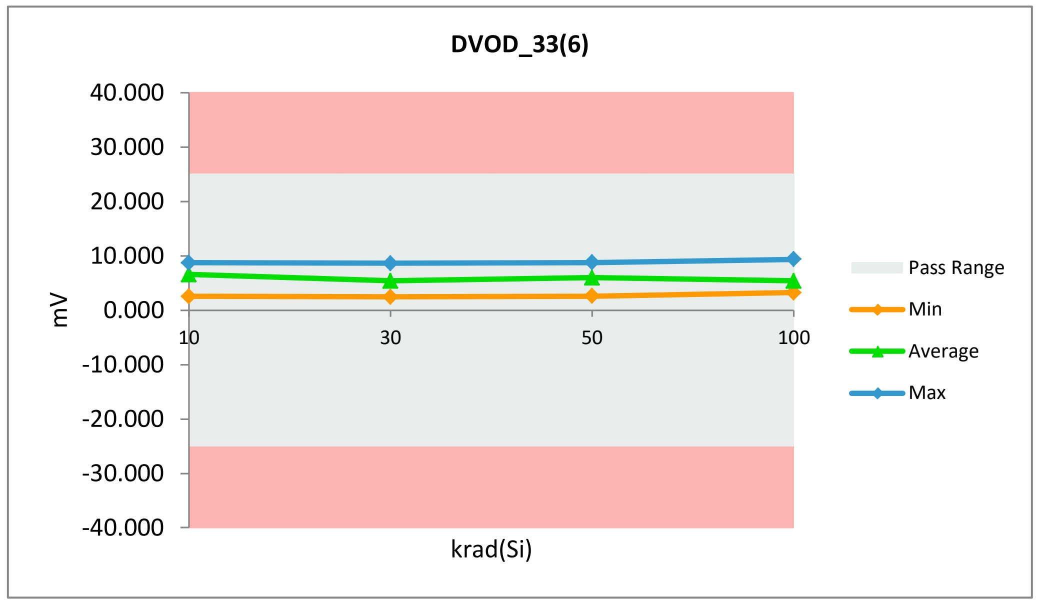


LDR Biased TID Report
SN55LVCP22A-SP

		DVOD_33(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.097	7.480	-2.383
10	5	7.547	7.476	0.071
10	7	5.103	6.256	-1.153
10	11	6.334	7.485	-1.152
10	15	6.320	6.250	0.071
10	20	3.873	2.572	1.301
10	21	5.106	6.257	-1.152
10	24	8.791	8.714	0.077
30	1	5.097	6.124	-1.027
30	5	7.547	6.104	1.443
30	7	5.103	4.928	0.175
30	11	6.334	6.159	0.175
30	15	6.320	4.884	1.436
30	20	3.873	2.469	1.404
30	21	5.106	3.710	1.396
30	24	8.791	8.612	0.179
50	1	5.097	6.295	-1.198
50	5	7.547	6.292	1.255
50	7	5.103	3.844	1.259
50	11	6.334	7.528	-1.194
50	15	6.320	7.520	-1.200
50	20	3.873	2.615	1.258
50	21	5.106	5.073	0.033
50	24	8.791	8.757	0.034
100	3	8.784	5.691	3.093
100	8	5.098	3.233	1.865
100	12	8.790	6.944	1.846
100	13	8.783	9.356	-0.573
100	16	5.099	4.456	0.643
100	17	6.327	4.458	1.869
100	18	5.101	5.650	-0.549
100	19	5.097	3.235	1.862
	Max	8.791	9.356	3.093
	Average	6.175	5.826	0.349
	Min	3.873	2.469	-2.383
	Std Dev	1.583	1.915	1.272



	DVOD_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.572	2.469	2.615	3.233
Average	6.561	5.374	5.991	5.378
Max	8.714	8.612	8.757	9.356
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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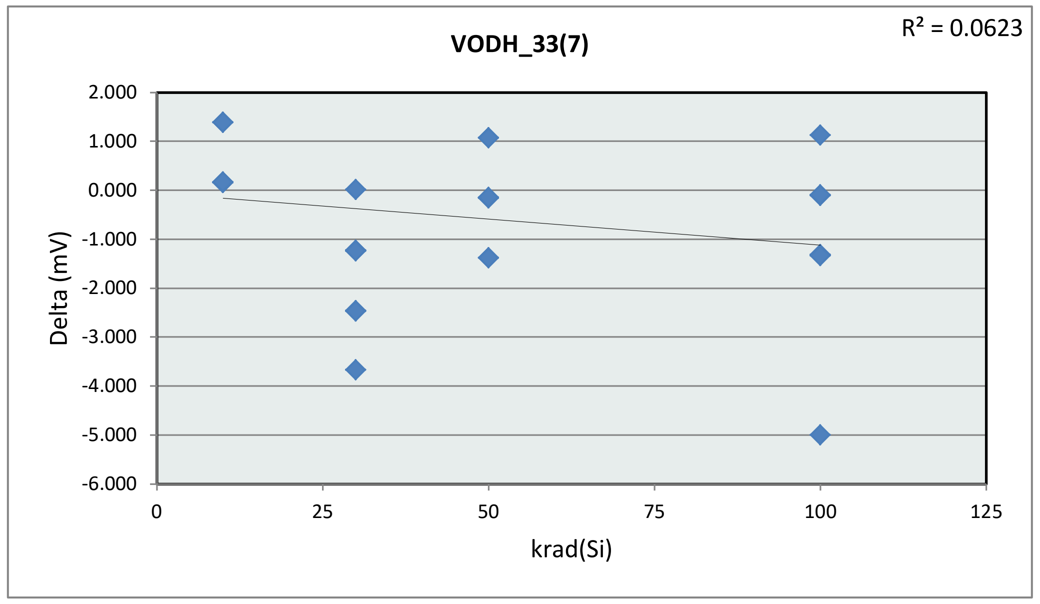
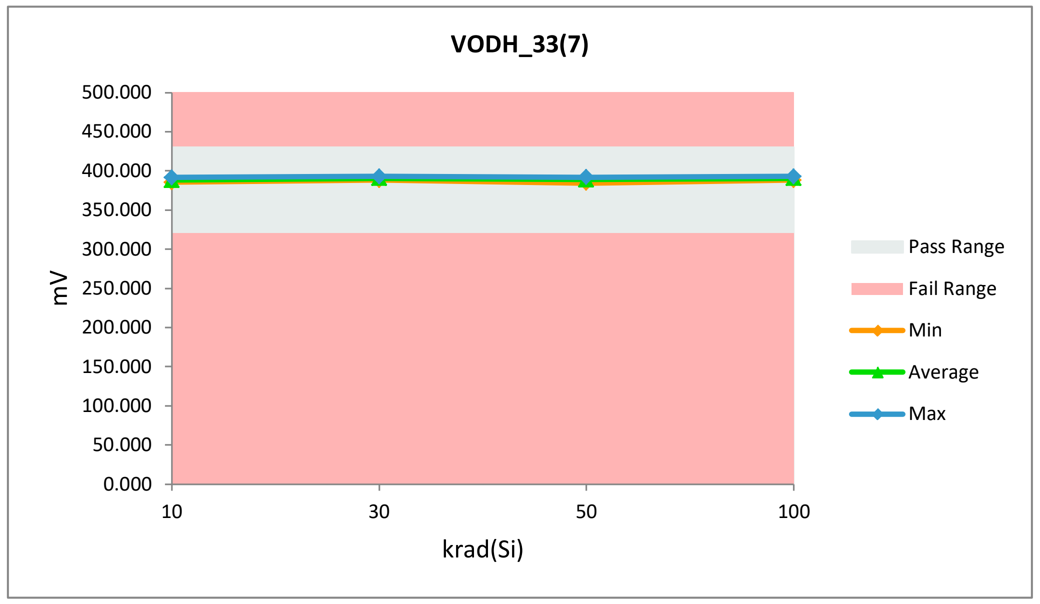
		VODH_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	388.001	387.842	0.159
10	5	392.908	391.520	1.388
10	7	389.226	389.065	0.161
10	11	390.459	389.074	1.385
10	15	389.230	387.843	1.387
10	20	386.776	386.618	0.158
10	21	385.547	385.389	0.158
10	24	388.002	387.843	0.159
30	1	388.001	390.458	-2.457
30	5	392.908	392.897	0.011
30	7	389.226	392.893	-3.667
30	11	390.459	391.688	-1.229
30	15	389.230	390.461	-1.231
30	20	386.776	388.020	-1.244
30	21	385.547	388.018	-2.471
30	24	388.002	389.240	-1.238
50	1	388.001	389.384	-1.383
50	5	392.908	391.838	1.070
50	7	389.226	389.384	-0.158
50	11	390.459	390.611	-0.152
50	15	389.230	389.384	-0.154
50	20	386.776	388.157	-1.381
50	21	385.547	384.475	1.072
50	24	388.002	388.157	-0.155
100	3	389.233	390.564	-1.331
100	8	388.000	388.111	-0.111
100	12	391.684	393.001	-1.317
100	13	389.230	389.338	-0.108
100	16	391.683	390.557	1.126
100	17	386.773	388.112	-1.339
100	18	388.002	393.002	-5.000
100	19	390.458	390.559	-0.101
	Max	392.908	393.002	1.388
	Average	388.922	389.484	-0.562
	Min	385.547	384.475	-5.000
	Std Dev	2.067	2.121	1.451



	VODH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	385.389	388.018	384.475	388.111
Average	388.149	390.459	388.924	390.406
Max	391.520	392.897	391.838	393.002
UL	430.000	430.000	430.000	430.000



LDR Biased TID Report
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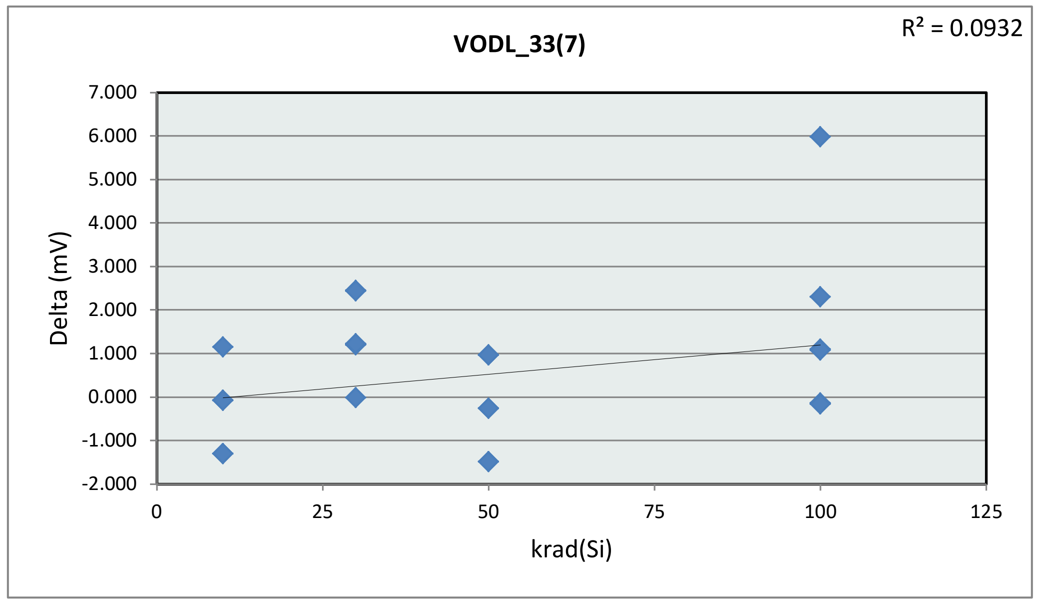
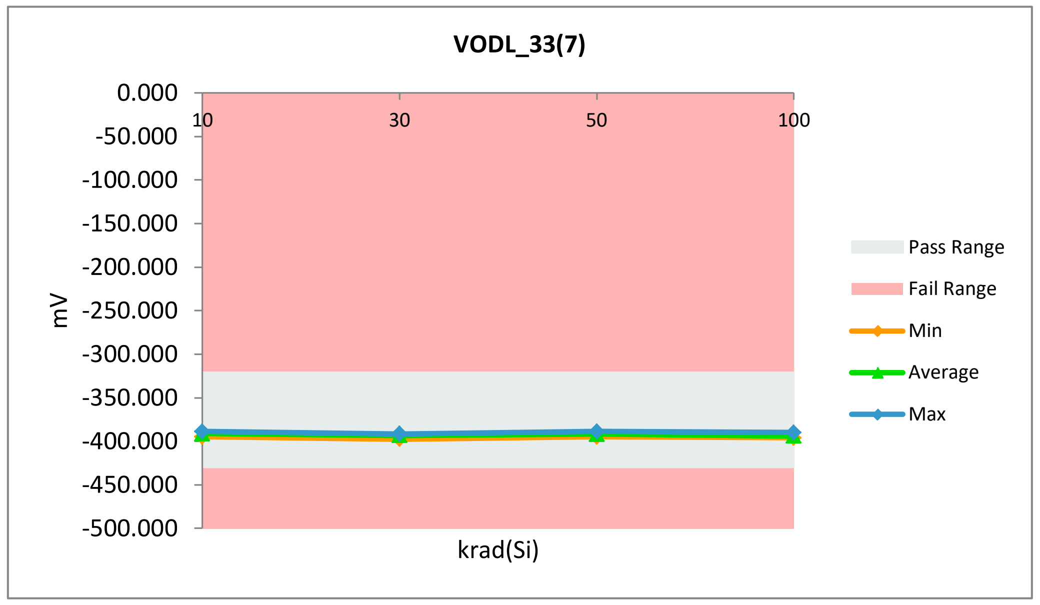
	VODL_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-391.347	-391.271	-0.076
10	5	-396.258	-394.955	-1.303
10	7	-392.577	-391.275	-1.302
10	11	-392.572	-391.266	-1.306
10	15	-388.891	-388.815	-0.076
10	20	-391.345	-391.268	-0.077
10	21	-390.119	-388.816	-1.303
10	24	-391.346	-392.496	1.150
30	1	-391.347	-392.558	1.211
30	5	-396.258	-397.450	1.192
30	7	-392.577	-393.787	1.210
30	11	-392.572	-392.550	-0.022
30	15	-388.891	-391.334	2.443
30	20	-391.345	-392.554	1.209
30	21	-390.119	-391.334	1.215
30	24	-391.346	-393.777	2.431
50	1	-391.347	-391.085	-0.262
50	5	-396.258	-394.766	-1.492
50	7	-392.577	-392.312	-0.265
50	11	-392.572	-392.312	-0.260
50	15	-388.891	-389.858	0.967
50	20	-391.345	-392.312	0.967
50	21	-390.119	-388.631	-1.488
50	24	-391.346	-392.312	0.966
100	3	-393.798	-393.647	-0.151
100	8	-388.893	-389.992	1.099
100	12	-395.028	-396.097	1.069
100	13	-393.800	-396.094	2.294
100	16	-391.347	-391.212	-0.135
100	17	-393.802	-393.656	-0.146
100	18	-388.891	-394.873	5.982
100	19	-396.254	-396.094	-0.160
	Max	-388.891	-388.631	5.982
	Average	-392.037	-392.524	0.487
	Min	-396.258	-397.450	-1.492
	Std Dev	2.247	2.229	1.510



	VODL_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-394.955	-397.450	-394.766	-396.097
Average	-391.270	-393.168	-391.699	-393.958
Max	-388.815	-391.334	-388.631	-389.992
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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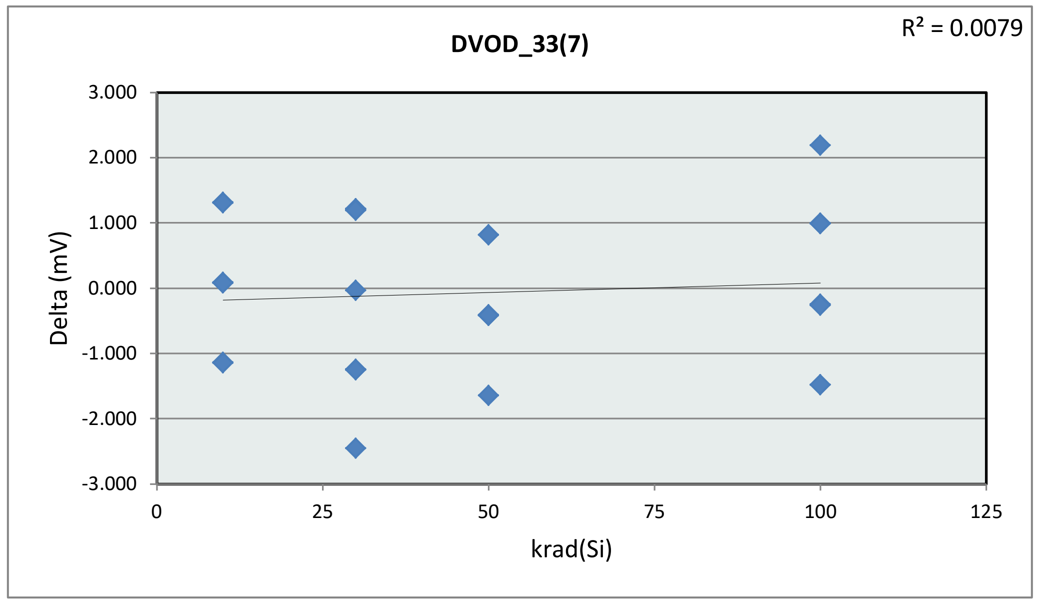
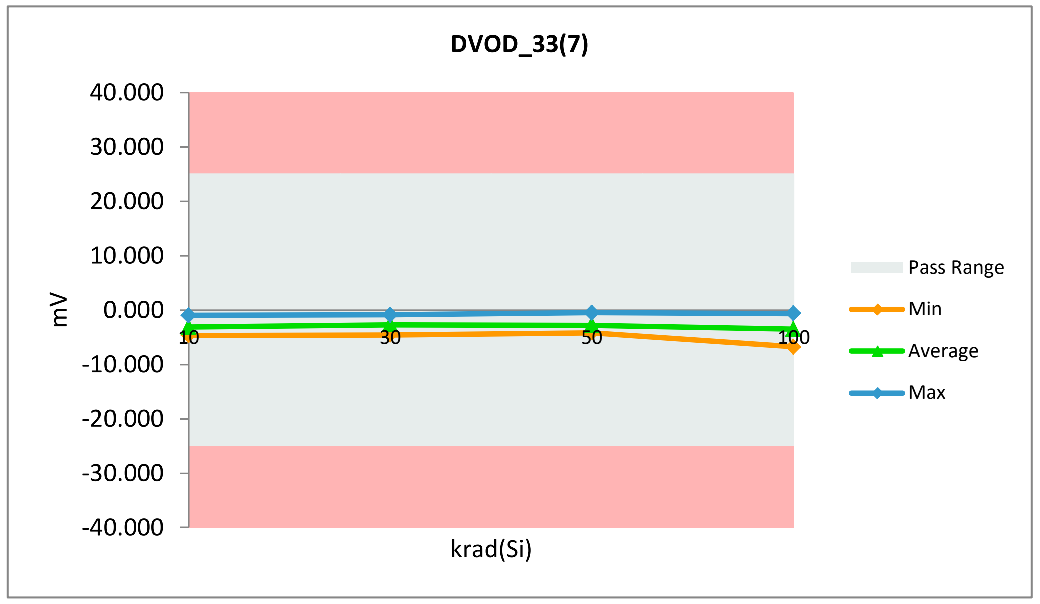
	DVOD_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-3.346	-3.428	0.083
10	5	-3.350	-3.435	0.085
10	7	-3.351	-2.210	-1.141
10	11	-2.113	-2.192	0.079
10	15	0.338	-0.972	1.310
10	20	-4.569	-4.650	0.081
10	21	-4.571	-3.426	-1.145
10	24	-3.344	-4.652	1.309
30	1	-3.346	-2.100	-1.246
30	5	-3.350	-4.553	1.203
30	7	-3.351	-0.894	-2.457
30	11	-2.113	-0.861	-1.251
30	15	0.338	-0.873	1.211
30	20	-4.569	-4.534	-0.035
30	21	-4.571	-3.316	-1.255
30	24	-3.344	-4.537	1.193
50	1	-3.346	-1.701	-1.645
50	5	-3.350	-2.928	-0.422
50	7	-3.351	-2.928	-0.423
50	11	-2.113	-1.701	-0.412
50	15	0.338	-0.474	0.812
50	20	-4.569	-4.155	-0.414
50	21	-4.571	-4.155	-0.416
50	24	-3.344	-4.155	0.812
100	3	-4.565	-3.083	-1.482
100	8	-0.893	-1.881	0.988
100	12	-3.345	-3.096	-0.249
100	13	-4.570	-6.756	2.186
100	16	0.336	-0.655	0.992
100	17	-7.029	-5.544	-1.485
100	18	-0.889	-1.871	0.982
100	19	-5.797	-5.535	-0.262
	Max	0.338	-0.474	2.186
	Average	-3.115	-3.039	-0.075
	Min	-7.029	-6.756	-2.457
	Std Dev	1.803	1.624	1.108



	DVOD_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-4.652	-4.553	-4.155	-6.756
Average	-3.121	-2.709	-2.775	-3.553
Max	-0.972	-0.861	-0.474	-0.655
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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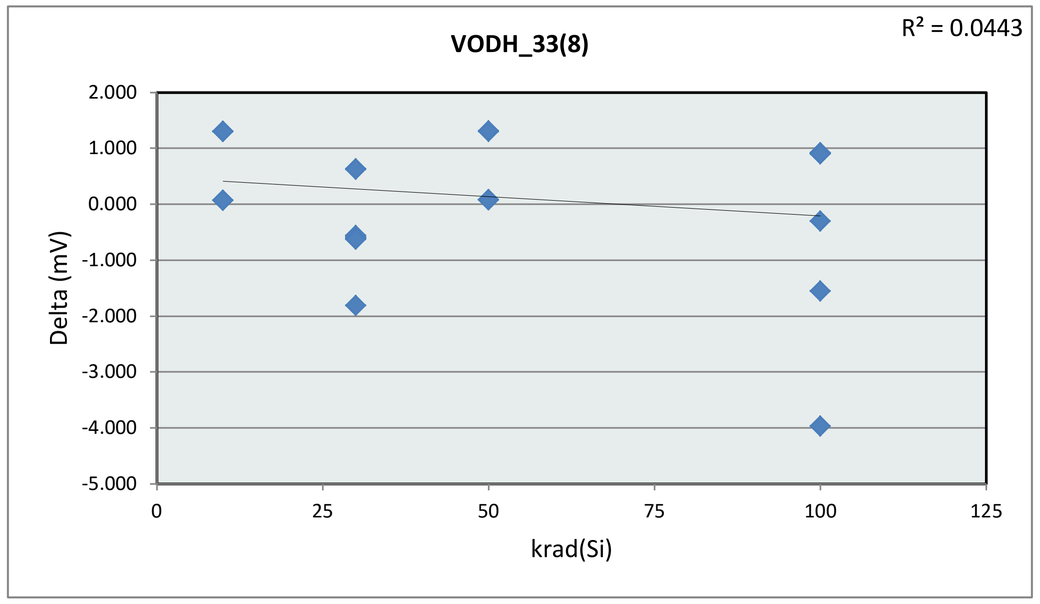
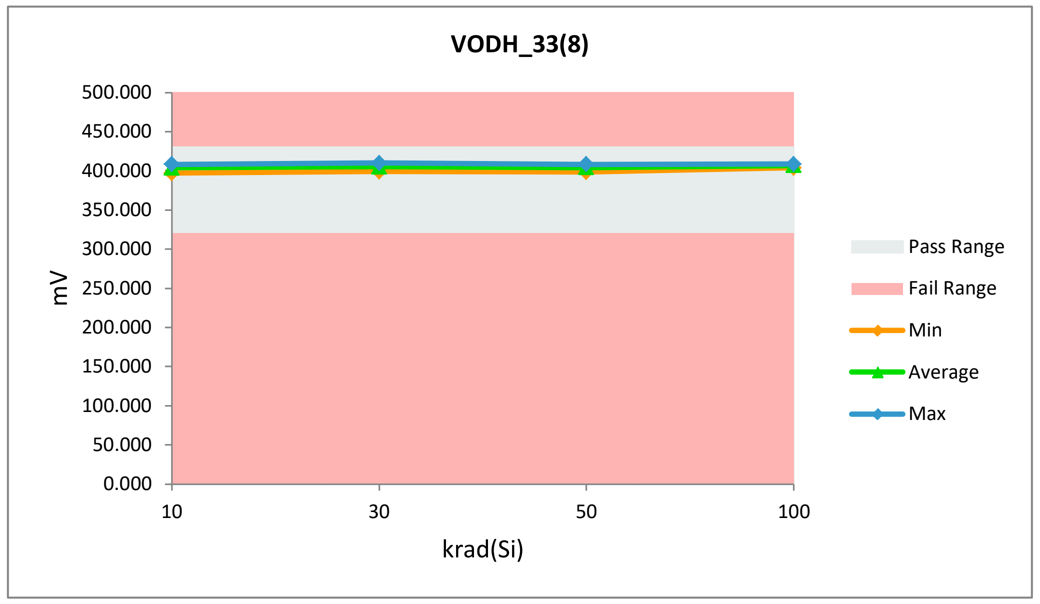
		VODH_33(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	405.828	405.761	0.067
10	5	409.509	408.214	1.295
10	7	404.604	403.307	1.297
10	11	407.061	406.991	0.070
10	15	403.371	403.304	0.067
10	20	400.920	399.624	1.296
10	21	398.467	397.170	1.297
10	24	407.061	405.764	1.297
30	1	405.828	405.193	0.635
30	5	409.509	410.073	-0.564
30	7	404.604	405.206	-0.602
30	11	407.061	408.877	-1.816
30	15	403.371	403.962	-0.591
30	20	400.920	401.532	-0.612
30	21	398.467	399.099	-0.632
30	24	407.061	406.438	0.623
50	1	405.828	405.754	0.074
50	5	409.509	408.207	1.302
50	7	404.604	404.528	0.076
50	11	407.061	406.984	0.077
50	15	403.371	403.298	0.073
50	20	400.920	400.845	0.075
50	21	398.467	398.392	0.075
50	24	407.061	405.757	1.304
100	3	409.513	408.599	0.914
100	8	404.601	403.703	0.898
100	12	405.833	407.393	-1.560
100	13	409.513	408.599	0.914
100	16	405.829	404.926	0.903
100	17	404.601	403.705	0.896
100	18	404.602	408.576	-3.974
100	19	408.284	408.593	-0.309
	Max	409.513	410.073	1.304
	Average	405.101	404.949	0.152
	Min	398.467	397.170	-3.974
	Std Dev	3.253	3.323	1.128

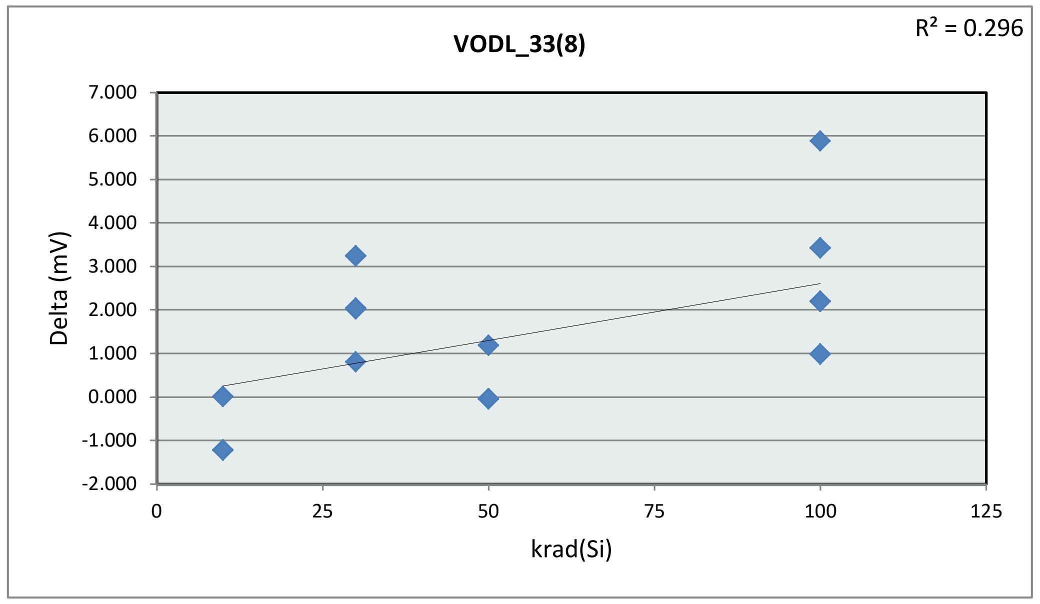


	VODH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	397.170	399.099	398.392	403.703
Average	403.767	405.048	404.221	406.762
Max	408.214	410.073	408.207	408.599
UL	430.000	430.000	430.000	430.000

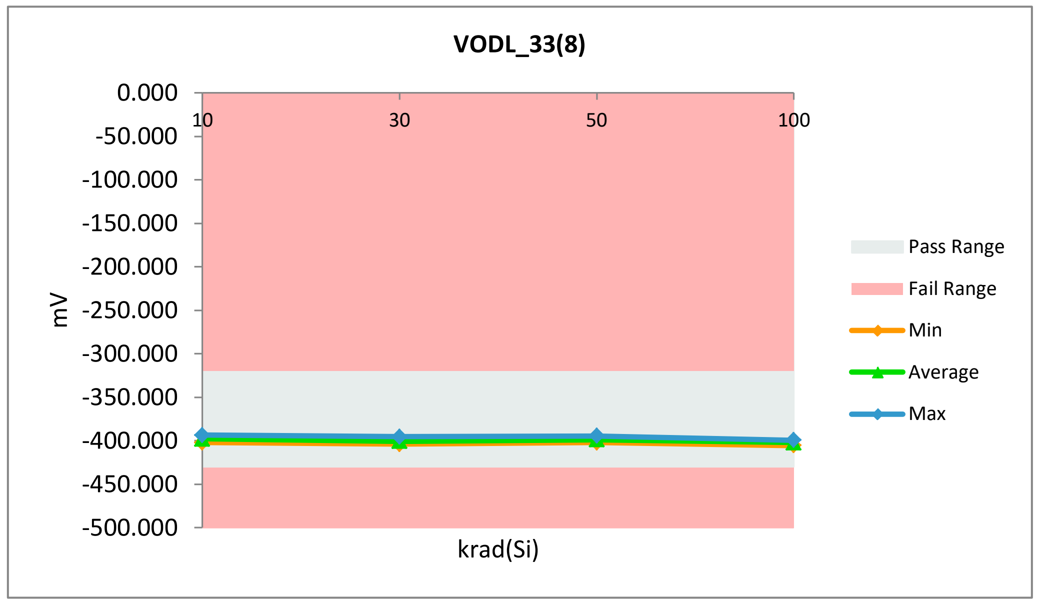


LDR Biased TID Report
SN55LVCP22A-SP

		VODL_33(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-399.507	-398.283	-1.224
10	5	-401.965	-401.967	0.002
10	7	-398.276	-398.281	0.005
10	11	-399.503	-399.507	0.004
10	15	-397.054	-395.829	-1.225
10	20	-397.050	-397.054	0.004
10	21	-394.592	-393.370	-1.222
10	24	-397.047	-397.052	0.005
30	1	-399.507	-401.529	2.022
30	5	-401.965	-403.981	2.016
30	7	-398.276	-401.514	3.238
30	11	-399.503	-402.732	3.229
30	15	-397.054	-399.092	2.038
30	20	-397.050	-399.078	2.028
30	21	-394.592	-395.398	0.806
30	24	-397.047	-400.285	3.238
50	1	-399.507	-399.461	-0.046
50	5	-401.965	-401.917	-0.048
50	7	-398.276	-399.459	1.183
50	11	-399.503	-399.458	-0.045
50	15	-397.054	-397.007	-0.047
50	20	-397.050	-398.232	1.182
50	21	-394.592	-394.548	-0.044
50	24	-397.047	-398.230	1.183
100	3	-400.733	-404.146	3.413
100	8	-398.279	-399.265	0.986
100	12	-398.275	-400.462	2.187
100	13	-398.278	-401.704	3.426
100	16	-399.507	-400.486	0.979
100	17	-398.279	-400.484	2.205
100	18	-399.505	-405.388	5.883
100	19	-403.190	-405.375	2.185
	Max	-394.592	-393.370	5.883
	Average	-398.470	-399.705	1.236
	Min	-403.190	-405.388	-1.225
	Std Dev	2.096	2.927	1.633



	VODL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-401.967	-403.981	-401.917	-405.388
Average	-397.668	-400.451	-398.539	-402.164
Max	-393.370	-395.398	-394.548	-399.265
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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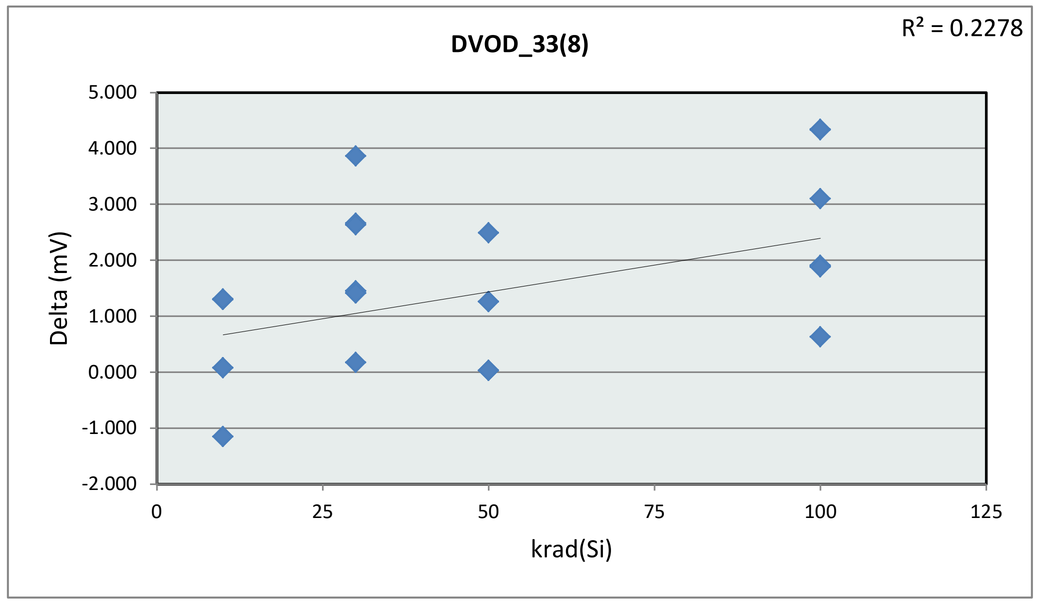
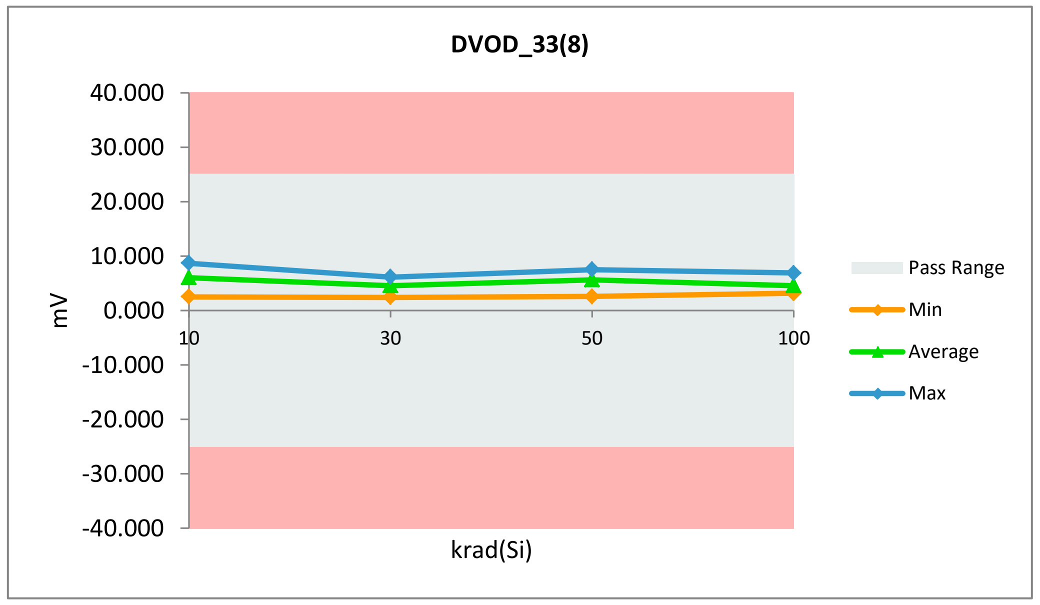
		DVOD_33(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	6.321	7.478	-1.157
10	5	7.543	6.247	1.297
10	7	6.328	5.027	1.301
10	11	7.558	7.483	0.074
10	15	6.317	7.475	-1.158
10	20	3.869	2.569	1.300
10	21	3.874	3.800	0.074
10	24	10.014	8.712	1.303
30	1	6.321	3.664	2.657
30	5	7.543	6.091	1.452
30	7	6.328	3.692	2.636
30	11	7.558	6.145	1.413
30	15	6.317	4.870	1.447
30	20	3.869	2.454	1.415
30	21	3.874	3.700	0.174
30	24	10.014	6.153	3.861
50	1	6.321	6.293	0.028
50	5	7.543	6.290	1.254
50	7	6.328	5.069	1.258
50	11	7.558	7.526	0.032
50	15	6.317	6.291	0.026
50	20	3.869	2.613	1.256
50	21	3.874	3.843	0.031
50	24	10.014	7.527	2.487
100	3	8.780	4.453	4.327
100	8	6.322	4.438	1.884
100	12	7.559	6.931	0.628
100	13	11.235	6.895	4.340
100	16	6.323	4.439	1.884
100	17	6.323	3.220	3.103
100	18	5.097	3.188	1.909
100	19	5.094	3.218	1.876
	Max	11.235	8.712	4.340
	Average	6.631	5.244	1.388
	Min	3.869	2.454	-1.158
	Std Dev	1.948	1.773	1.365



	DVOD_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.569	2.454	2.613	3.188
Average	6.099	4.596	5.682	4.598
Max	8.712	6.153	7.527	6.931
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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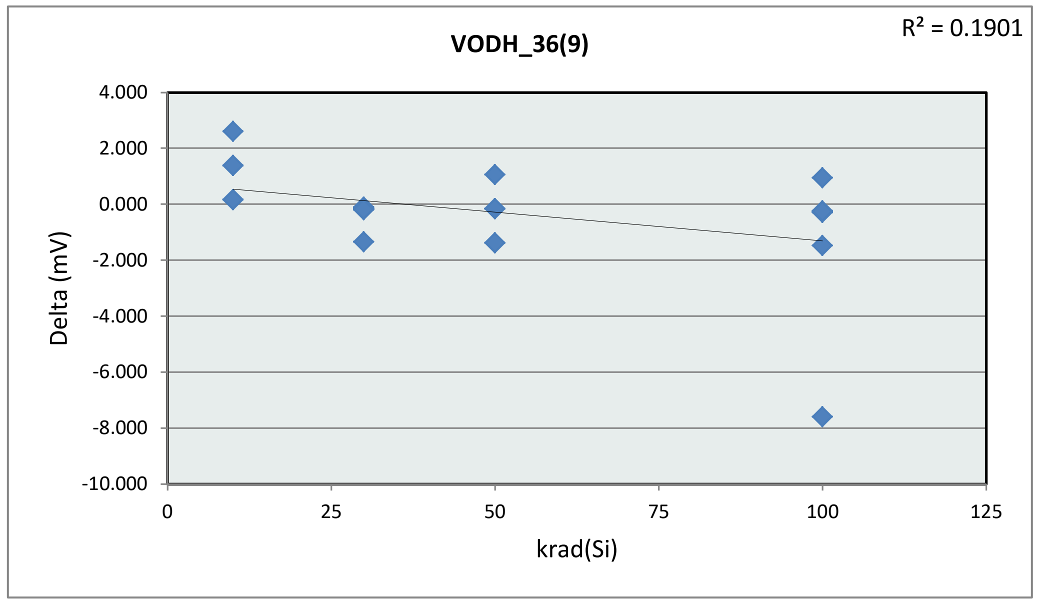
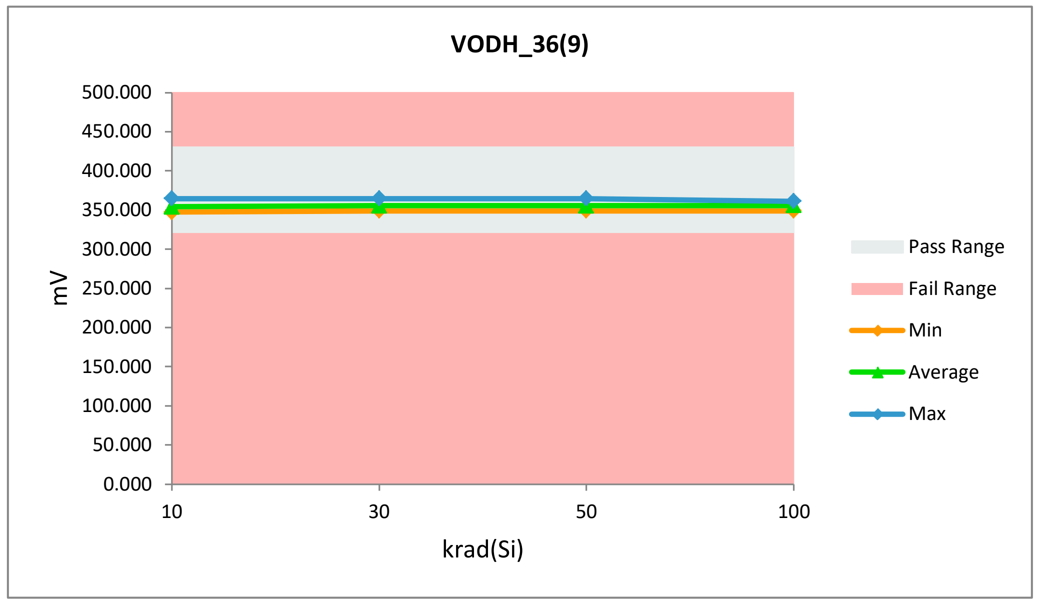
	VODH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	358.542	358.390	0.152
10	5	364.677	364.522	0.155
10	7	363.449	363.294	0.155
10	11	354.863	353.487	1.376
10	15	349.951	347.348	2.603
10	20	348.725	347.350	1.375
10	21	352.406	351.029	1.377
10	24	348.724	348.575	0.149
30	1	358.542	358.688	-0.146
30	5	364.677	364.791	-0.114
30	7	363.449	364.788	-1.339
30	11	354.863	355.031	-0.168
30	15	349.951	350.138	-0.187
30	20	348.725	348.920	-0.195
30	21	352.406	352.583	-0.177
30	24	348.724	348.917	-0.193
50	1	358.542	358.705	-0.163
50	5	364.677	363.614	1.063
50	7	363.449	364.841	-1.392
50	11	354.863	356.251	-1.388
50	15	349.951	350.115	-0.164
50	20	348.725	348.888	-0.163
50	21	352.406	352.569	-0.163
50	24	348.724	348.888	-0.164
100	3	359.774	360.020	-0.246
100	8	353.631	353.901	-0.270
100	12	356.088	357.569	-1.481
100	13	348.725	349.020	-0.295
100	16	351.178	350.238	0.940
100	17	356.087	356.346	-0.259
100	18	353.634	361.236	-7.602
100	19	357.316	357.571	-0.255
	Max	364.677	364.841	2.603
	Average	355.014	355.238	-0.224
	Min	348.724	347.348	-7.602
	Std Dev	5.547	5.913	1.599



	VODH_36(9)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	430	mV
Min Limit	320	mV

krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	347.348	348.917	348.888	349.020
Average	354.249	355.482	355.484	355.738
Max	364.522	364.791	364.841	361.236
UL	430.000	430.000	430.000	430.000



LDR Biased TID Report
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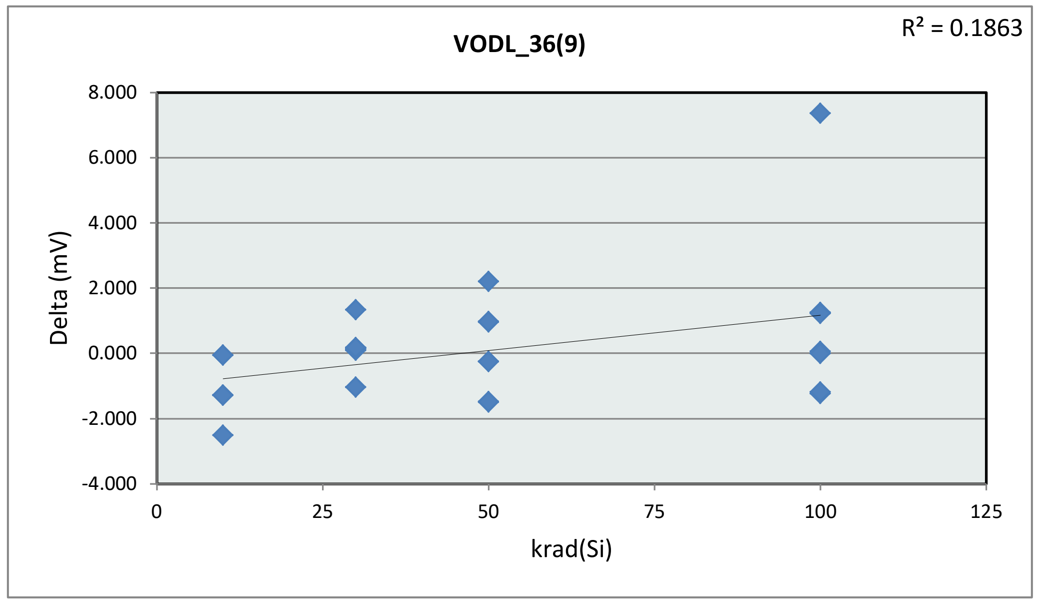
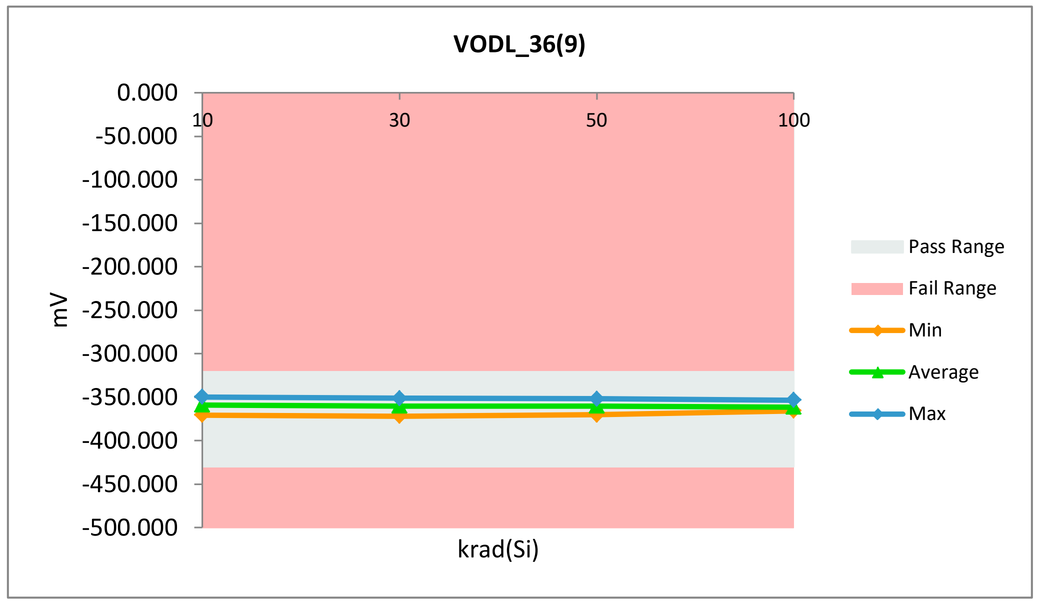
	VODL_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-363.122	-361.829	-1.293
10	5	-371.716	-370.421	-1.295
10	7	-366.807	-366.741	-0.066
10	11	-358.210	-356.917	-1.293
10	15	-352.076	-349.559	-2.517
10	20	-354.530	-354.466	-0.064
10	21	-358.212	-356.920	-1.292
10	24	-355.758	-354.467	-1.291
30	1	-363.122	-363.250	0.128
30	5	-371.716	-371.807	0.091
30	7	-366.807	-368.144	1.337
30	11	-358.210	-358.357	0.147
30	15	-352.076	-351.034	-1.042
30	20	-354.530	-354.697	0.167
30	21	-358.212	-358.362	0.150
30	24	-355.758	-355.920	0.162
50	1	-363.122	-362.861	-0.261
50	5	-371.716	-370.224	-1.492
50	7	-366.807	-367.769	0.962
50	11	-358.210	-359.179	0.969
50	15	-352.076	-351.816	-0.260
50	20	-354.530	-356.725	2.195
50	21	-358.212	-356.725	-1.487
50	24	-355.758	-355.497	-0.261
100	3	-366.800	-365.559	-1.241
100	8	-358.214	-357.019	-1.195
100	12	-361.895	-363.123	1.228
100	13	-355.757	-357.014	1.257
100	16	-353.304	-353.353	0.049
100	17	-364.350	-364.346	-0.004
100	18	-356.984	-364.342	7.358
100	19	-364.348	-365.564	1.216
	Max	-352.076	-349.559	7.358
	Average	-360.092	-360.125	0.033
	Min	-371.716	-371.807	-2.517
	Std Dev	5.940	6.082	1.710



	VODL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-370.421	-371.807	-370.224	-365.564
Average	-358.915	-360.196	-360.100	-361.290
Max	-349.559	-351.034	-351.816	-353.353
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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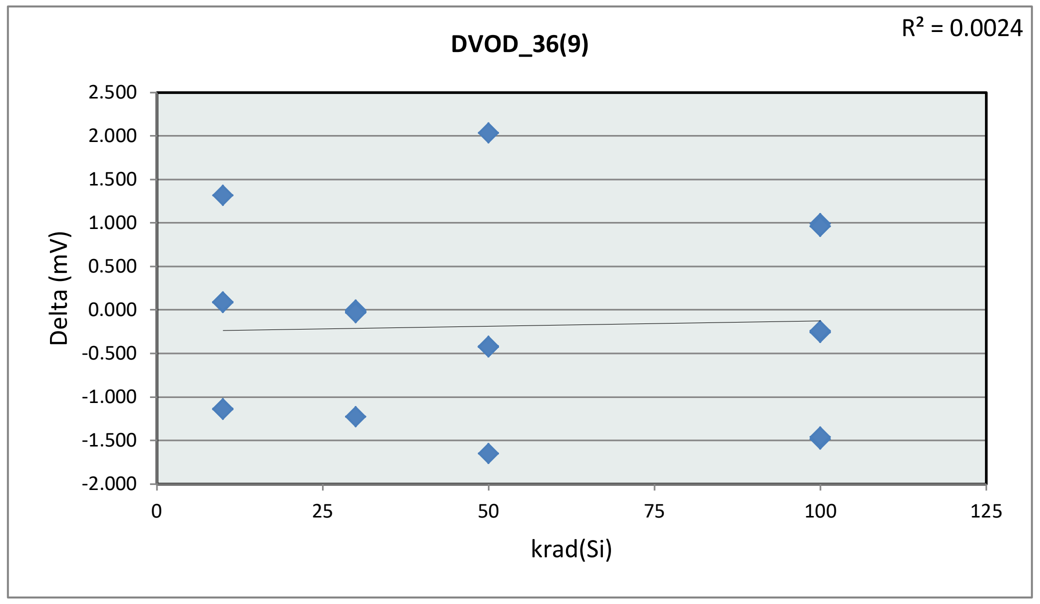
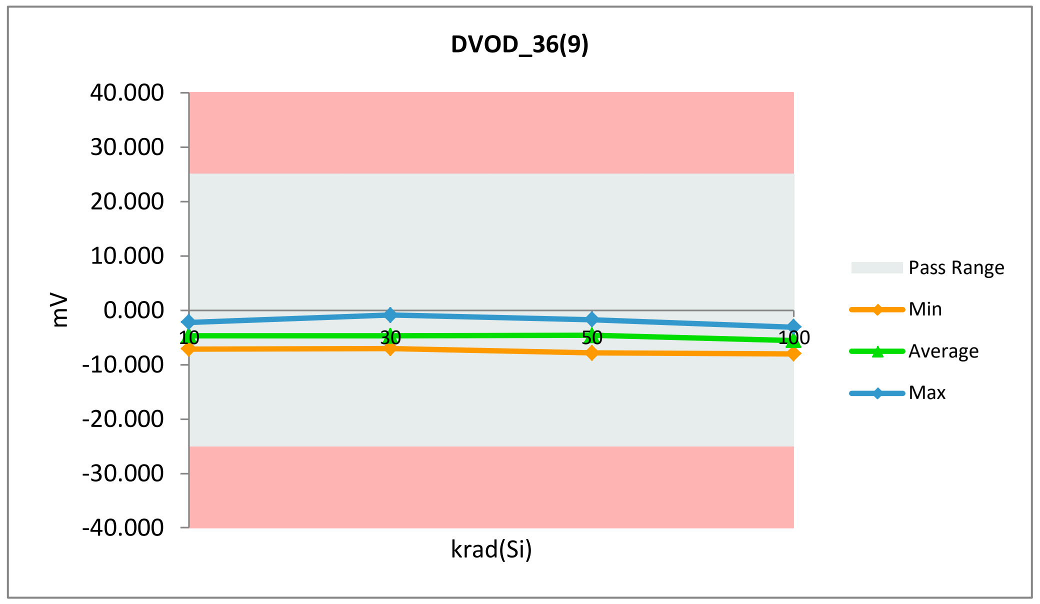
	DVOD_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-4.580	-3.439	-1.141
10	5	-7.039	-5.900	-1.139
10	7	-3.358	-3.448	0.090
10	11	-3.347	-3.431	0.083
10	15	-2.125	-2.211	0.087
10	20	-5.804	-7.116	1.312
10	21	-5.805	-5.891	0.085
10	24	-7.034	-5.892	-1.142
30	1	-4.580	-4.562	-0.018
30	5	-7.039	-7.015	-0.024
30	7	-3.358	-3.356	-0.002
30	11	-3.347	-3.326	-0.021
30	15	-2.125	-0.896	-1.229
30	20	-5.804	-5.777	-0.027
30	21	-5.805	-5.779	-0.026
30	24	-7.034	-7.002	-0.032
50	1	-4.580	-4.156	-0.424
50	5	-7.039	-6.610	-0.429
50	7	-3.358	-2.929	-0.429
50	11	-3.347	-2.928	-0.419
50	15	-2.125	-1.701	-0.423
50	20	-5.804	-7.837	2.032
50	21	-5.805	-4.155	-1.650
50	24	-7.034	-6.610	-0.424
100	3	-7.026	-5.539	-1.487
100	8	-4.583	-3.118	-1.465
100	12	-5.807	-5.554	-0.253
100	13	-7.032	-7.993	0.961
100	16	-2.127	-3.115	0.988
100	17	-8.263	-8.000	-0.263
100	18	-3.350	-3.106	-0.244
100	19	-7.031	-7.993	0.962
	Max	-2.125	-0.896	2.032
	Average	-5.078	-4.887	-0.191
	Min	-8.263	-8.000	-1.650
	Std Dev	1.840	2.014	0.829



	DVOD_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-7.116	-7.015	-7.837	-8.000
Average	-4.666	-4.714	-4.616	-5.552
Max	-2.211	-0.896	-1.701	-3.106
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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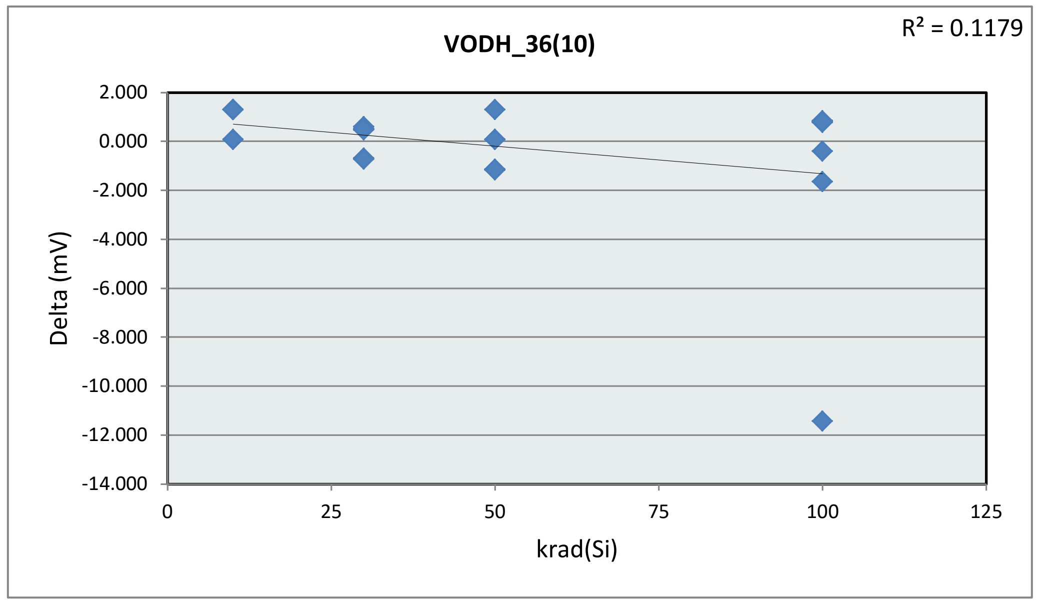
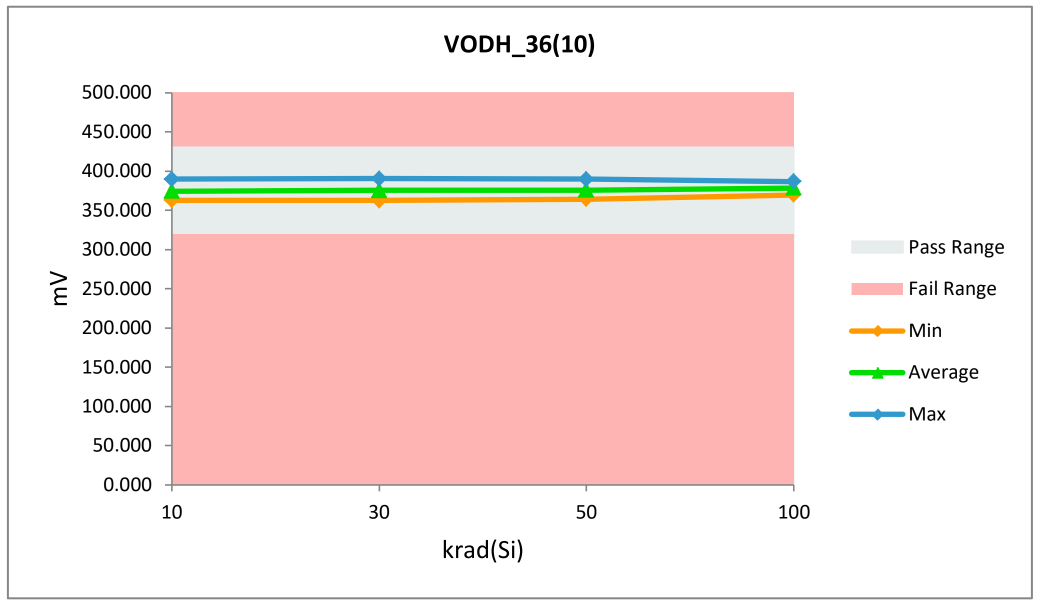
		VODH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	377.587	377.523	0.064
10	5	391.089	389.798	1.291
10	7	377.591	376.298	1.293
10	11	377.591	376.299	1.292
10	15	370.219	368.929	1.290
10	20	362.856	362.793	0.063
10	21	371.454	370.161	1.293
10	24	373.909	372.616	1.293
30	1	377.587	378.281	-0.694
30	5	391.089	390.495	0.594
30	7	377.591	377.073	0.518
30	11	377.591	377.074	0.517
30	15	370.219	370.936	-0.717
30	20	362.856	362.394	0.462
30	21	371.454	370.965	0.489
30	24	373.909	374.633	-0.724
50	1	377.587	378.747	-1.160
50	5	391.089	389.792	1.297
50	7	377.591	377.521	0.070
50	11	377.591	378.749	-1.158
50	15	370.219	370.153	0.066
50	20	362.856	364.017	-1.161
50	21	371.454	371.385	0.069
50	24	373.909	375.067	-1.158
100	3	387.410	386.575	0.835
100	8	373.904	373.123	0.781
100	12	378.820	378.036	0.784
100	13	375.133	376.792	-1.659
100	16	370.222	369.457	0.765
100	17	377.588	376.794	0.794
100	18	372.678	384.110	-11.432
100	19	382.498	382.902	-0.404
	Max	391.089	390.495	1.297
	Average	375.786	375.922	-0.136
	Min	362.856	362.394	-11.432
	Std Dev	7.252	7.201	2.244



	VODH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	362.793	362.394	364.017	369.457
Average	374.302	375.231	375.679	378.474
Max	389.798	390.495	389.792	386.575
UL	430.000	430.000	430.000	430.000



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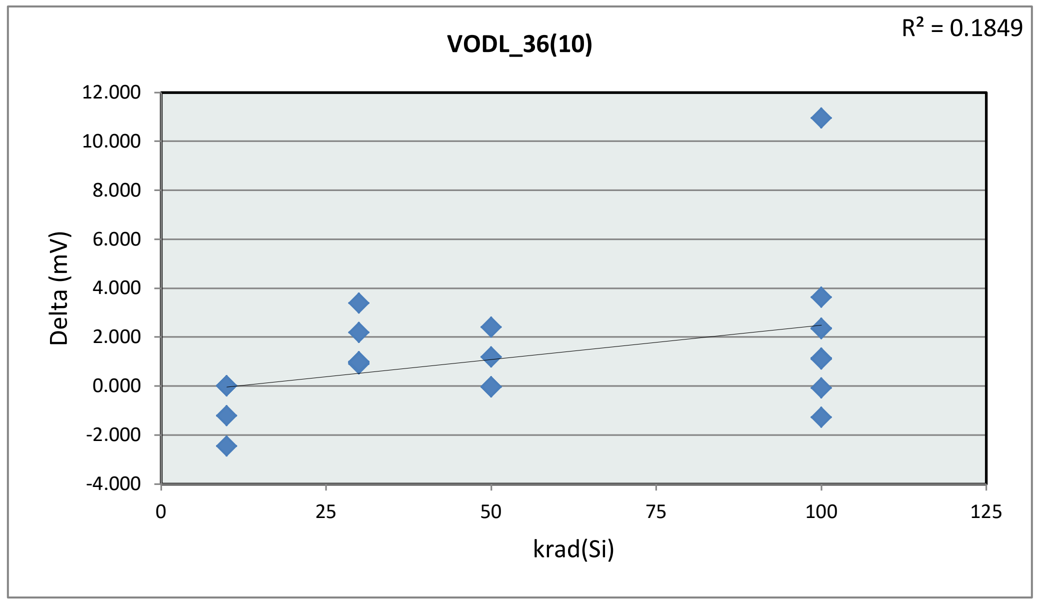
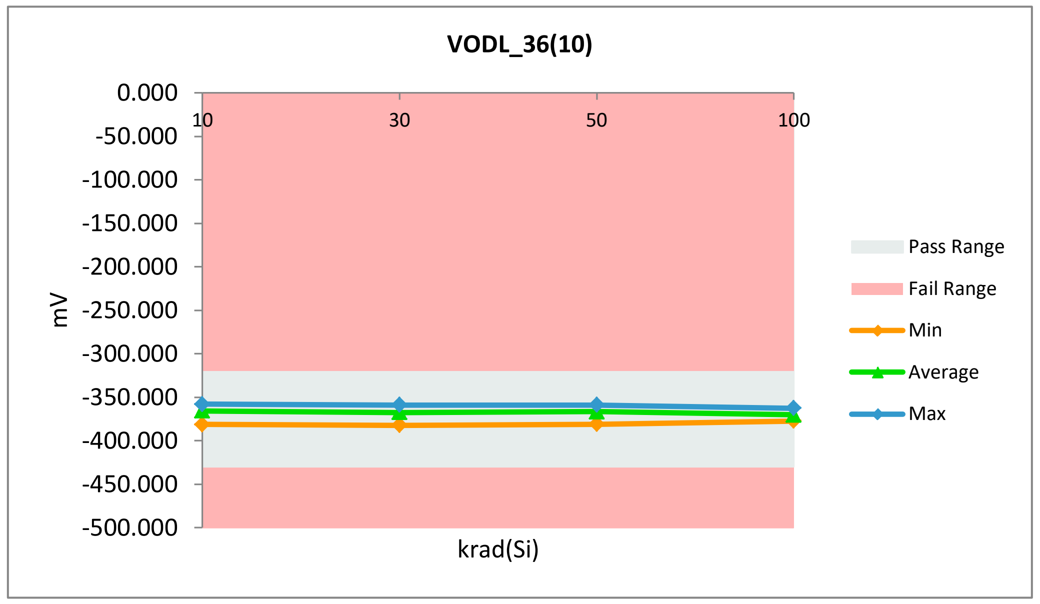
		VODL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-370.049	-370.052	0.003
10	5	-381.100	-381.102	0.002
10	7	-368.818	-368.823	0.005
10	11	-365.134	-365.139	0.005
10	15	-360.231	-357.778	-2.453
10	20	-357.772	-357.777	0.005
10	21	-363.906	-363.912	0.006
10	24	-361.451	-360.229	-1.222
30	1	-370.049	-370.991	0.942
30	5	-381.100	-382.001	0.901
30	7	-368.818	-372.198	3.380
30	11	-365.134	-367.307	2.173
30	15	-360.231	-361.223	0.992
30	20	-357.772	-358.765	0.993
30	21	-363.906	-364.861	0.955
30	24	-361.451	-362.417	0.966
50	1	-370.049	-370.005	-0.044
50	5	-381.100	-381.053	-0.047
50	7	-368.818	-371.230	2.412
50	11	-365.134	-366.320	1.186
50	15	-360.231	-360.187	-0.044
50	20	-357.772	-358.957	1.185
50	21	-363.906	-363.865	-0.041
50	24	-361.451	-361.410	-0.041
100	3	-373.730	-376.060	2.330
100	8	-366.367	-366.292	-0.075
100	12	-365.133	-366.267	1.134
100	13	-361.455	-365.067	3.612
100	16	-363.911	-362.624	-1.287
100	17	-368.820	-371.175	2.355
100	18	-365.137	-376.080	10.943
100	19	-376.187	-377.290	1.103
	Max	-357.772	-357.777	10.943
	Average	-366.441	-367.452	1.010
	Min	-381.100	-382.001	-2.453
	Std Dev	6.548	6.997	2.222



	VODL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-381.102	-382.001	-381.053	-377.290
Average	-365.602	-367.470	-366.628	-370.107
Max	-357.777	-358.765	-358.957	-362.624
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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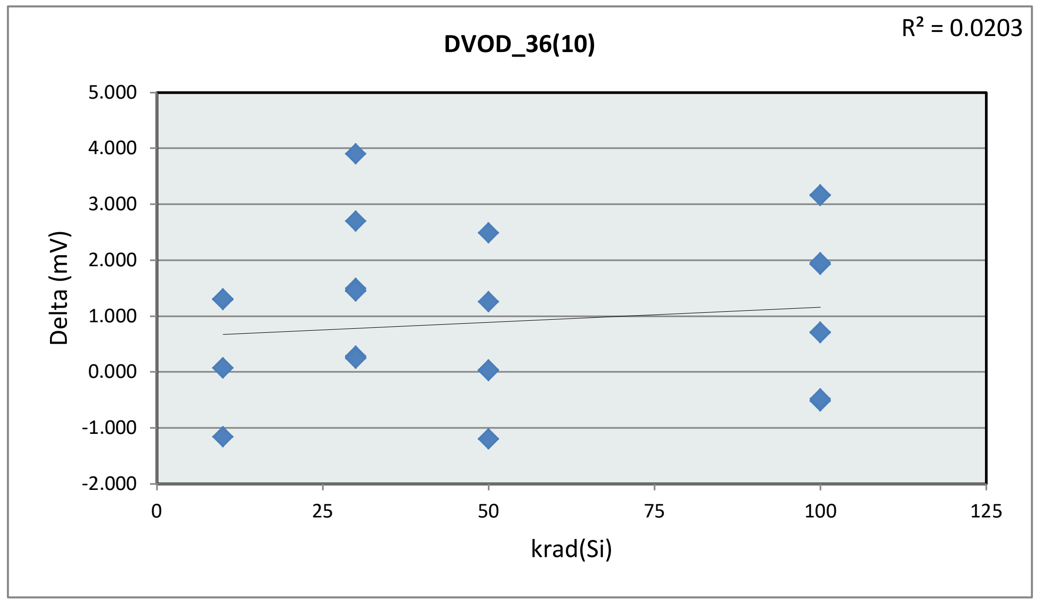
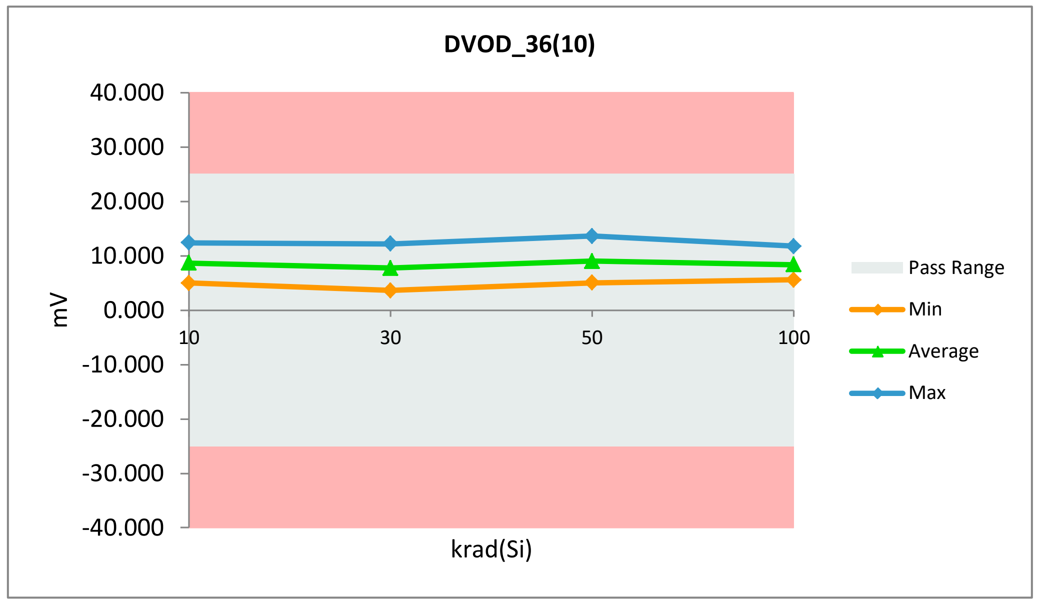
		DVOD_36(10)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	7.538	7.471	0.067
10	5	9.989	8.696	1.293
10	7	8.773	7.476	1.297
10	11	12.457	11.159	1.298
10	15	9.988	11.151	-1.162
10	20	5.084	5.017	0.067
10	21	7.547	6.249	1.298
10	24	12.458	12.387	0.071
30	1	7.538	7.290	0.248
30	5	9.989	8.493	1.496
30	7	8.773	4.875	3.898
30	11	12.457	9.767	2.690
30	15	9.988	9.713	0.275
30	20	5.084	3.629	1.455
30	21	7.547	6.104	1.443
30	24	12.458	12.217	0.241
50	1	7.538	8.741	-1.204
50	5	9.989	8.739	1.250
50	7	8.773	6.291	2.482
50	11	12.457	12.429	0.028
50	15	9.988	9.966	0.022
50	20	5.084	5.060	0.024
50	21	7.547	7.520	0.028
50	24	12.458	13.657	-1.199
100	3	13.680	10.516	3.164
100	8	7.537	6.831	0.706
100	12	13.687	11.769	1.918
100	13	13.678	11.726	1.952
100	16	6.311	6.833	-0.522
100	17	8.768	5.619	3.149
100	18	7.542	8.030	-0.488
100	19	6.311	5.612	0.699
	Max	13.687	13.657	3.898
	Average	9.344	8.470	0.874
	Min	5.084	3.629	-1.204
	Std Dev	2.647	2.658	1.298



	DVOD_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	5.017	3.629	5.060	5.612
Average	8.701	7.761	9.050	8.367
Max	12.387	12.217	13.657	11.769
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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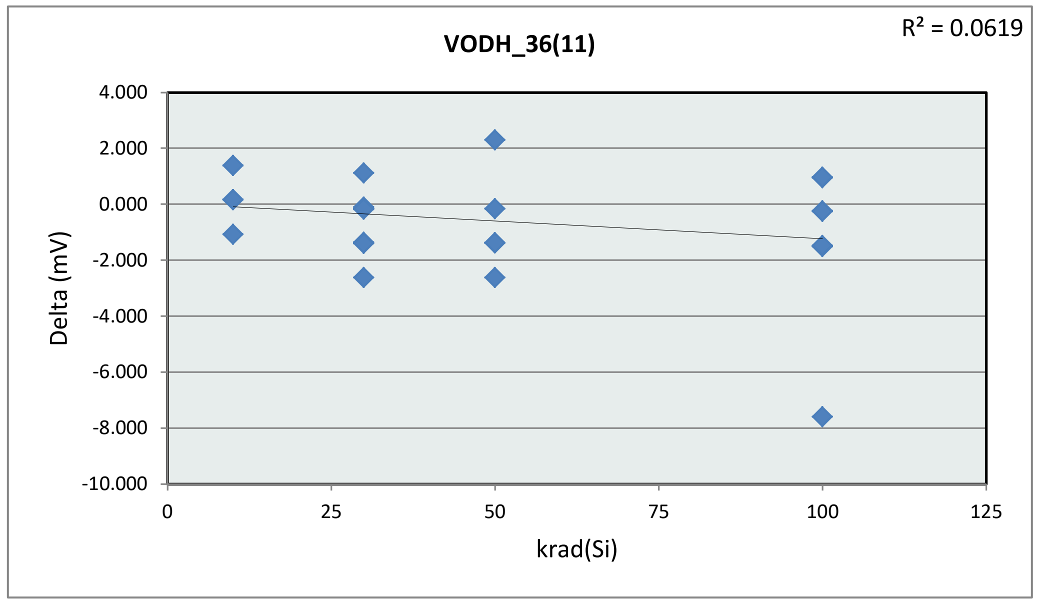
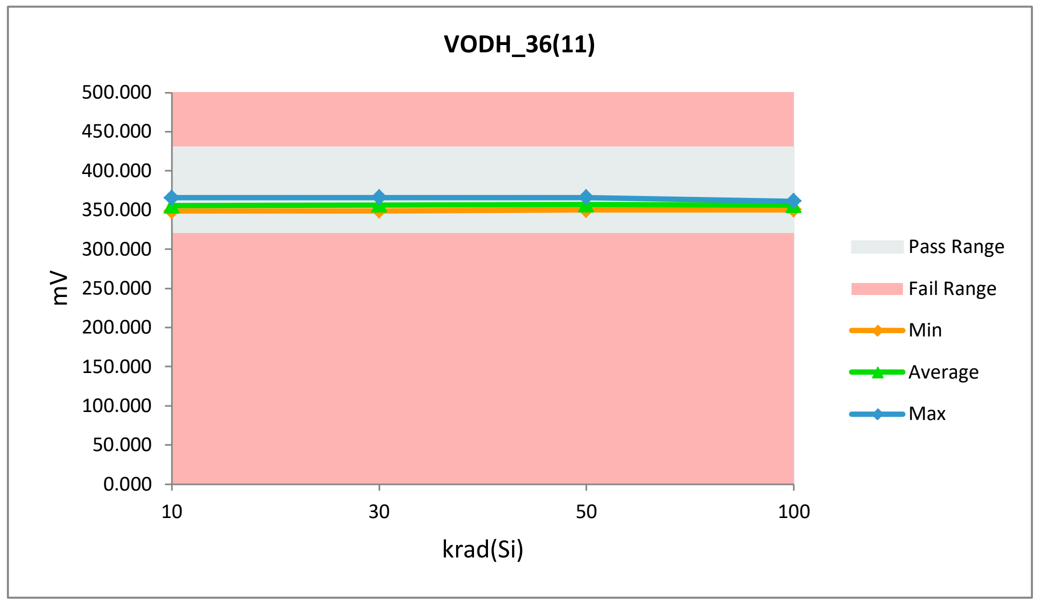
	VODH_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	358.541	358.388	0.153
10	5	367.130	365.746	1.384
10	7	364.675	364.518	0.157
10	11	354.862	354.711	0.151
10	15	349.950	349.800	0.150
10	20	348.724	348.575	0.149
10	21	353.633	352.255	1.378
10	24	348.723	349.800	-1.077
30	1	358.541	359.906	-1.365
30	5	367.130	366.009	1.121
30	7	364.675	364.785	-0.110
30	11	354.862	355.028	-0.166
30	15	349.950	351.356	-1.406
30	20	348.724	348.916	-0.192
30	21	353.633	353.801	-0.168
30	24	348.723	351.356	-2.633
50	1	358.541	361.159	-2.618
50	5	367.130	364.841	2.289
50	7	364.675	366.068	-1.393
50	11	354.862	356.251	-1.389
50	15	349.950	351.342	-1.392
50	20	348.724	350.115	-1.391
50	21	353.633	353.797	-0.164
50	24	348.723	350.115	-1.392
100	3	359.772	360.018	-0.246
100	8	354.857	353.899	0.958
100	12	357.314	357.566	-0.252
100	13	348.723	350.240	-1.517
100	16	352.404	351.457	0.947
100	17	356.086	355.123	0.963
100	18	353.633	361.234	-7.601
100	19	357.315	358.790	-1.475
	Max	367.130	366.068	2.289
	Average	355.588	356.155	-0.567
	Min	348.723	348.575	-7.601
	Std Dev	6.091	5.755	1.740



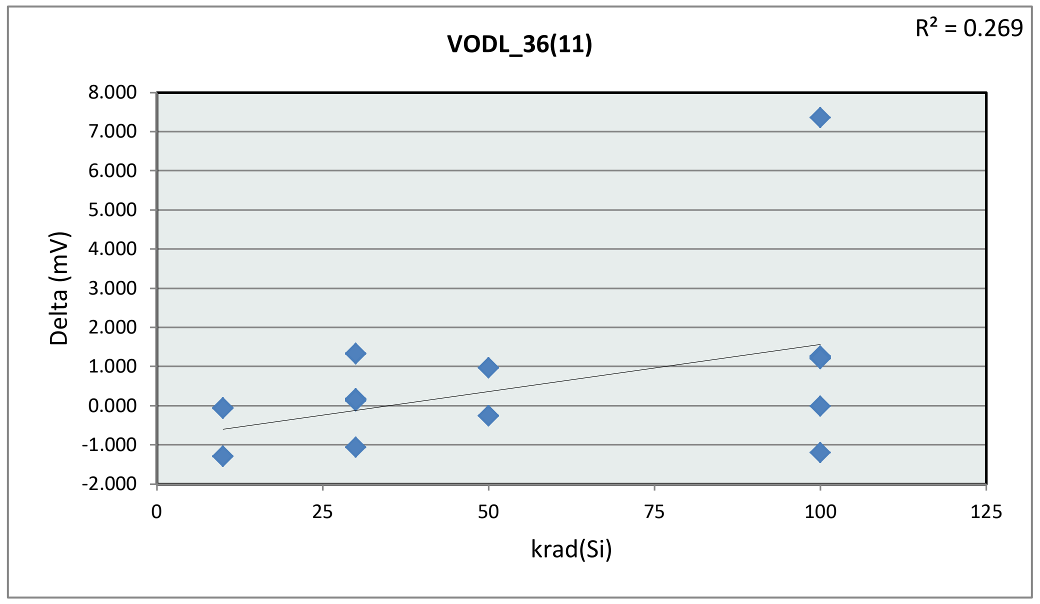
	VODH_36(11)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	430	mV
Min Limit	320	mV

krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	348.575	348.916	350.115	350.240
Average	355.474	356.395	356.711	356.041
Max	365.746	366.009	366.068	361.234
UL	430.000	430.000	430.000	430.000

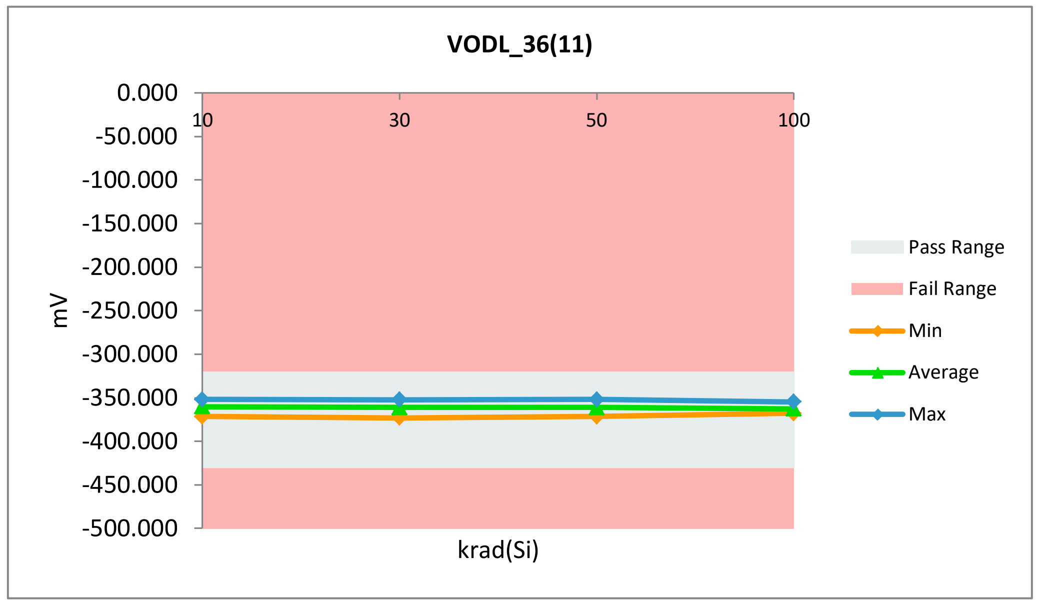


LDR Biased TID Report
SN55LVCP22A-SP

		VODL_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-364.350	-363.058	-1.292
10	5	-371.716	-371.650	-0.066
10	7	-368.035	-366.743	-1.292
10	11	-359.439	-358.146	-1.293
10	15	-352.077	-352.015	-0.062
10	20	-355.758	-355.695	-0.063
10	21	-359.440	-358.149	-1.291
10	24	-356.986	-355.696	-1.290
30	1	-364.350	-364.476	0.126
30	5	-371.716	-373.032	1.316
30	7	-368.035	-369.369	1.334
30	11	-359.439	-359.582	0.143
30	15	-352.077	-352.259	0.182
30	20	-355.758	-355.921	0.163
30	21	-359.440	-359.587	0.147
30	24	-356.986	-355.924	-1.062
50	1	-364.350	-365.315	0.965
50	5	-371.716	-371.451	-0.265
50	7	-368.035	-368.996	0.961
50	11	-359.439	-359.179	-0.260
50	15	-352.077	-351.816	-0.261
50	20	-355.758	-356.725	0.967
50	21	-359.440	-359.179	-0.261
50	24	-356.986	-356.725	-0.261
100	3	-366.801	-368.004	1.203
100	8	-359.443	-358.243	-1.200
100	12	-361.896	-363.126	1.230
100	13	-356.986	-358.238	1.252
100	16	-353.305	-354.577	1.272
100	17	-365.578	-366.791	1.213
100	18	-358.213	-365.566	7.353
100	19	-366.804	-366.788	-0.016
	Max	-352.077	-351.816	7.353
	Average	-361.013	-361.313	0.300
	Min	-371.716	-373.032	-1.293
	Std Dev	5.917	6.162	1.571



	VODL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-371.650	-373.032	-371.451	-368.004
Average	-360.144	-361.269	-361.173	-362.667
Max	-352.015	-352.259	-351.816	-354.577
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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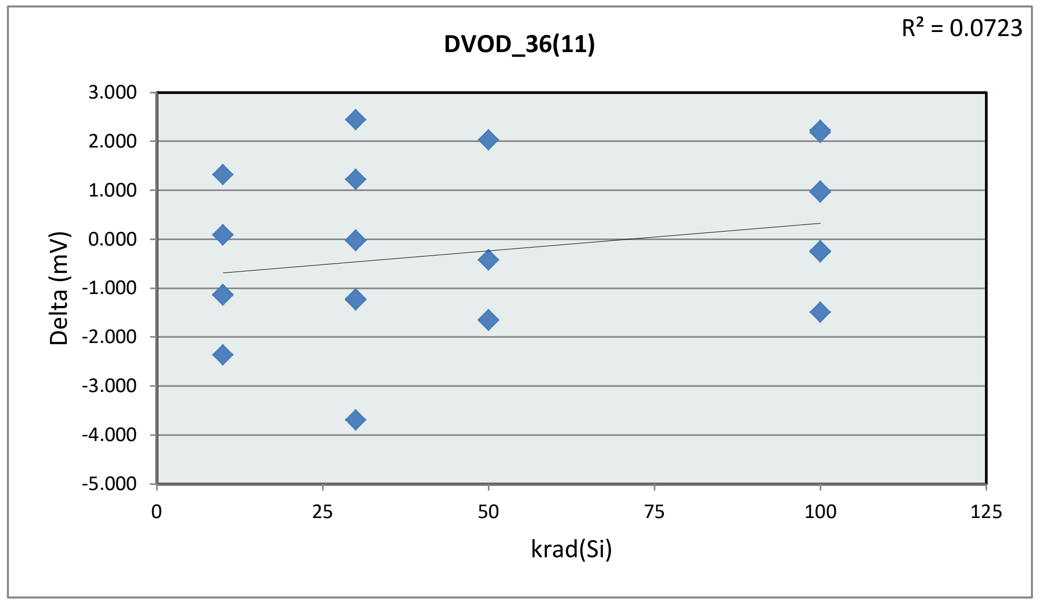
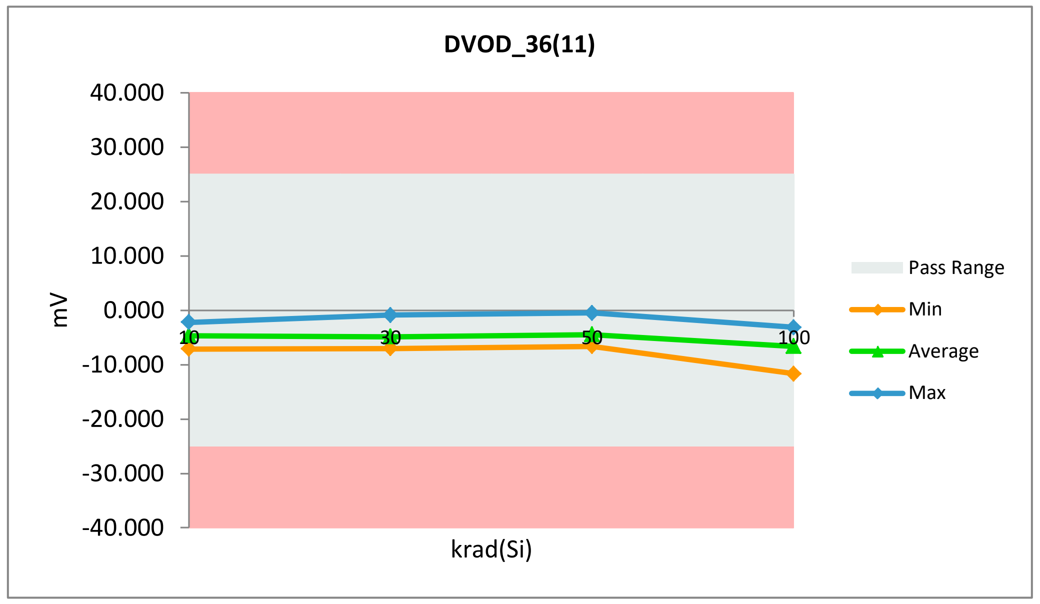
		DVOD_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-5.810	-4.670	-1.139
10	5	-4.586	-5.904	1.317
10	7	-3.360	-2.224	-1.136
10	11	-4.577	-3.435	-1.142
10	15	-2.127	-2.216	0.088
10	20	-7.034	-7.120	0.086
10	21	-5.808	-5.894	0.086
10	24	-8.264	-5.896	-2.367
30	1	-5.810	-4.570	-1.240
30	5	-4.586	-7.023	2.437
30	7	-3.360	-4.584	1.224
30	11	-4.577	-4.554	-0.023
30	15	-2.127	-0.903	-1.224
30	20	-7.034	-7.005	-0.029
30	21	-5.808	-5.786	-0.022
30	24	-8.264	-4.567	-3.697
50	1	-5.810	-4.155	-1.654
50	5	-4.586	-6.610	2.024
50	7	-3.360	-2.928	-0.432
50	11	-4.577	-2.928	-1.649
50	15	-2.127	-0.474	-1.653
50	20	-7.034	-6.610	-0.424
50	21	-5.808	-5.382	-0.425
50	24	-8.264	-6.610	-1.654
100	3	-7.029	-7.986	0.957
100	8	-4.585	-4.344	-0.241
100	12	-4.582	-5.560	0.978
100	13	-8.262	-7.998	-0.264
100	16	-0.902	-3.119	2.217
100	17	-9.493	-11.669	2.176
100	18	-4.580	-4.332	-0.248
100	19	-9.488	-7.998	-1.490
	Max	-0.902	-0.474	2.437
	Average	-5.426	-5.158	-0.268
	Min	-9.493	-11.669	-3.697
	Std Dev	2.191	2.301	1.421



	DVOD_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-7.120	-7.023	-6.610	-11.669
Average	-4.670	-4.874	-4.462	-6.626
Max	-2.216	-0.903	-0.474	-3.119
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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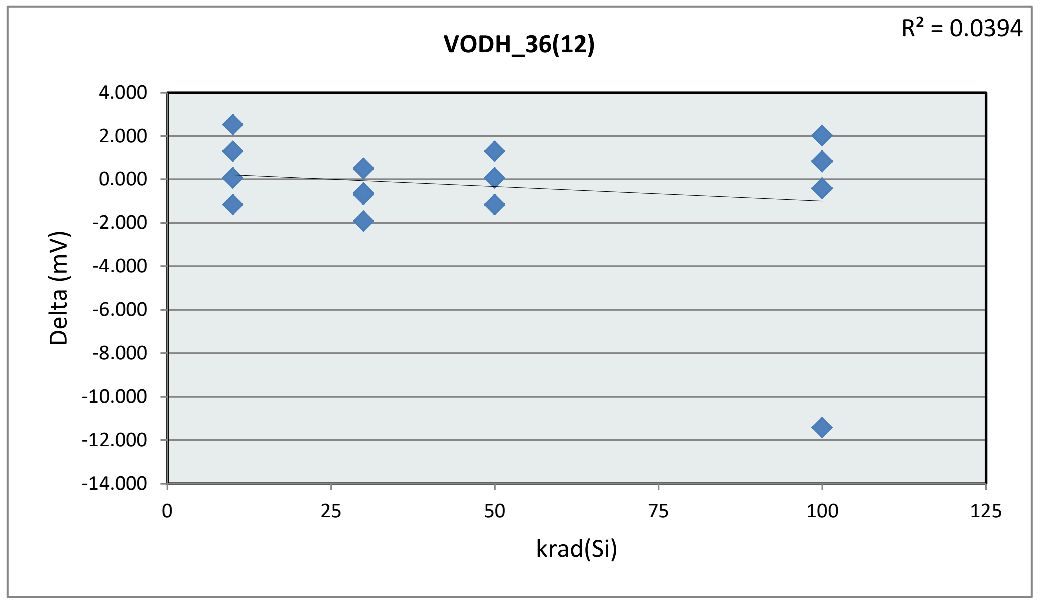
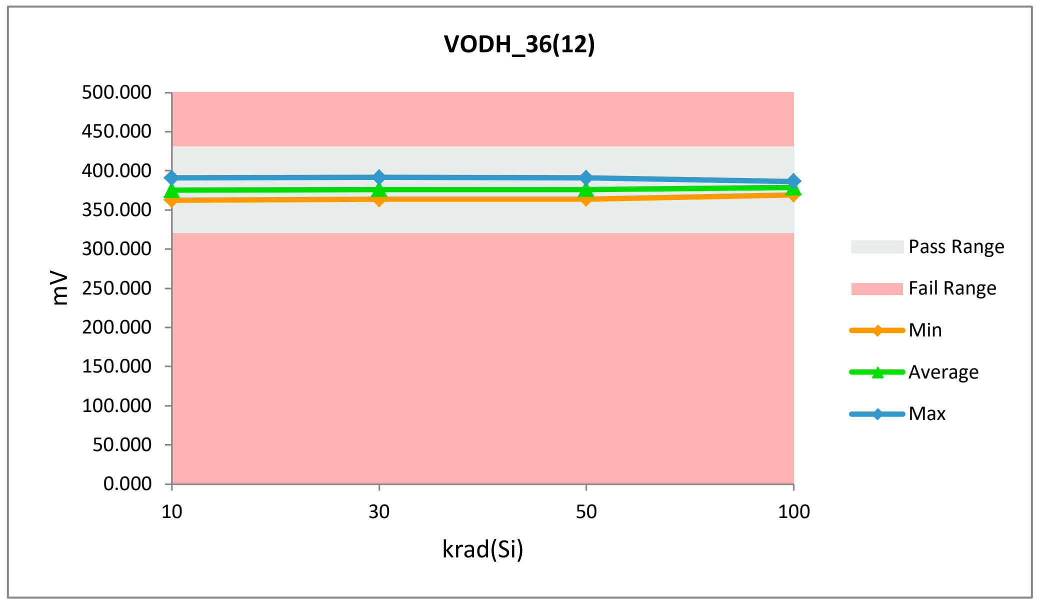
		VODH_36(12)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	377.586	377.523	0.063
10	5	391.087	391.024	0.063
10	7	377.589	377.525	0.064
10	11	377.590	377.525	0.065
10	15	370.217	371.383	-1.166
10	20	364.082	362.792	1.290
10	21	372.680	370.160	2.520
10	24	375.135	373.843	1.292
30	1	377.586	378.275	-0.689
30	5	391.087	391.711	-0.624
30	7	377.589	378.289	-0.700
30	11	377.590	378.291	-0.701
30	15	370.217	372.153	-1.936
30	20	364.082	363.609	0.473
30	21	372.680	372.182	0.498
30	24	375.135	374.627	0.508
50	1	377.586	378.746	-1.160
50	5	391.087	391.019	0.068
50	7	377.589	378.748	-1.159
50	11	377.590	378.748	-1.158
50	15	370.217	371.379	-1.162
50	20	364.082	364.017	0.065
50	21	372.680	371.384	1.296
50	24	375.135	375.066	0.069
100	3	387.409	386.568	0.841
100	8	373.903	373.116	0.787
100	12	377.591	378.029	-0.438
100	13	376.359	376.787	-0.428
100	16	371.448	369.450	1.998
100	17	378.815	376.787	2.028
100	18	372.676	384.103	-11.427
100	19	383.724	384.118	-0.394
	Max	391.087	391.711	2.520
	Average	376.244	376.531	-0.286
	Min	364.082	362.792	-11.427
	Std Dev	6.961	7.275	2.289



	VODH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	362.792	363.609	364.017	369.450
Average	375.222	376.142	376.138	378.620
Max	391.024	391.711	391.019	386.568
UL	430.000	430.000	430.000	430.000



LDR Biased TID Report
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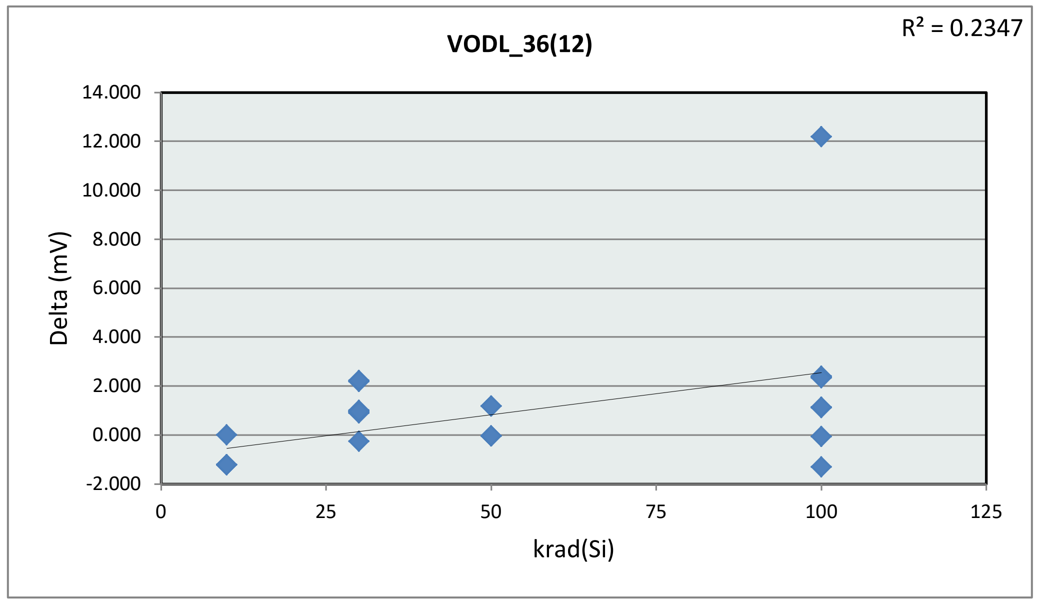
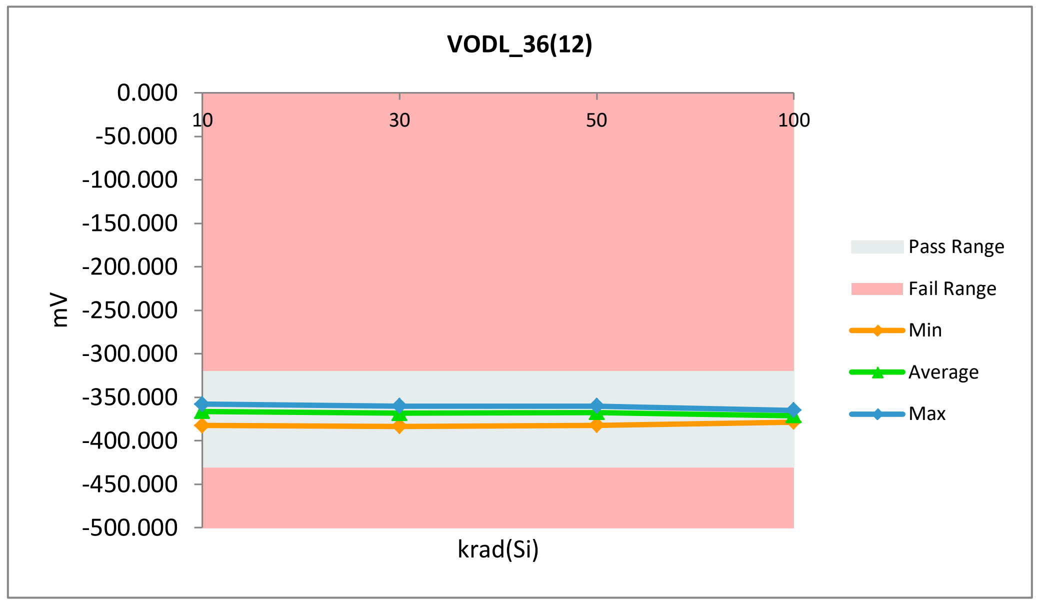
		VODL_36(12)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		-320	-320	
Min Limit		-430	-430	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-370.051	-368.826	-1.225
10	5	-382.329	-382.330	0.001
10	7	-371.275	-370.051	-1.224
10	11	-366.363	-365.141	-1.222
10	15	-360.232	-359.007	-1.225
10	20	-359.001	-357.777	-1.224
10	21	-365.135	-363.913	-1.222
10	24	-362.680	-361.458	-1.222
30	1	-370.051	-372.219	2.168
30	5	-382.329	-383.229	0.900
30	7	-371.275	-372.205	0.930
30	11	-366.363	-367.314	0.951
30	15	-360.232	-362.452	2.220
30	20	-359.001	-359.995	0.994
30	21	-365.135	-366.089	0.954
30	24	-362.680	-362.423	-0.257
50	1	-370.051	-371.233	1.182
50	5	-382.329	-382.282	-0.047
50	7	-371.275	-371.231	-0.044
50	11	-366.363	-367.548	1.185
50	15	-360.232	-360.187	-0.045
50	20	-359.001	-360.185	1.184
50	21	-365.135	-365.093	-0.042
50	24	-362.680	-362.638	-0.042
100	3	-376.187	-377.290	1.103
100	8	-367.596	-366.299	-1.297
100	12	-366.362	-368.717	2.355
100	13	-362.684	-365.072	2.388
100	16	-365.140	-365.076	-0.064
100	17	-370.049	-371.182	1.133
100	18	-365.138	-377.309	12.171
100	19	-376.188	-378.519	2.331
	Max	-359.001	-357.777	12.171
	Average	-367.517	-368.259	0.742
	Min	-382.329	-383.229	-1.297
	Std Dev	6.673	7.088	2.411



	VODL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-382.330	-383.229	-382.282	-378.519
Average	-366.063	-368.241	-367.550	-371.183
Max	-357.777	-359.995	-360.185	-365.072
UL	-320.000	-320.000	-320.000	-320.000



LDR Biased TID Report
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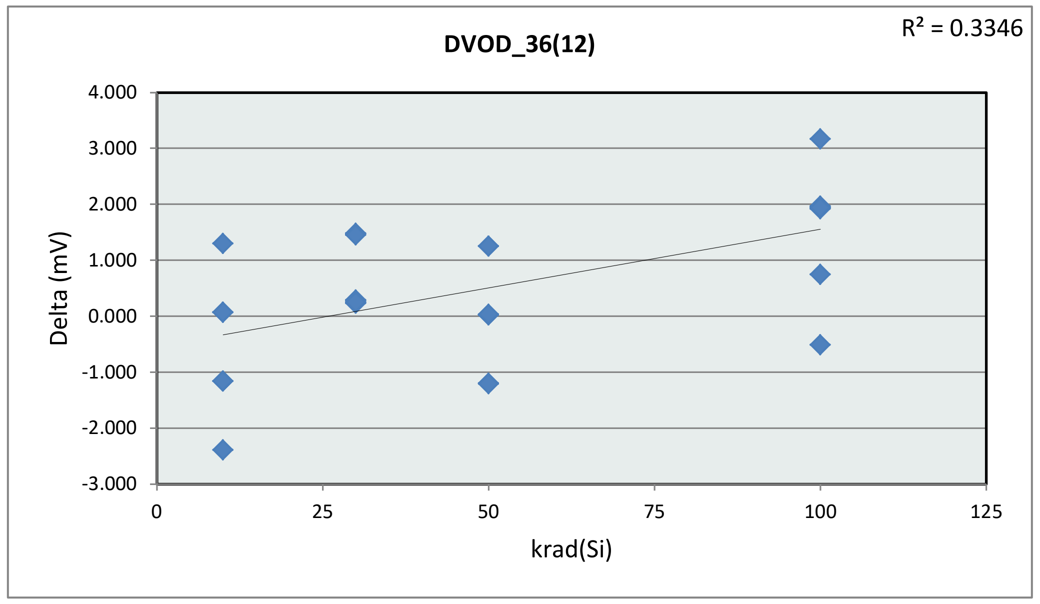
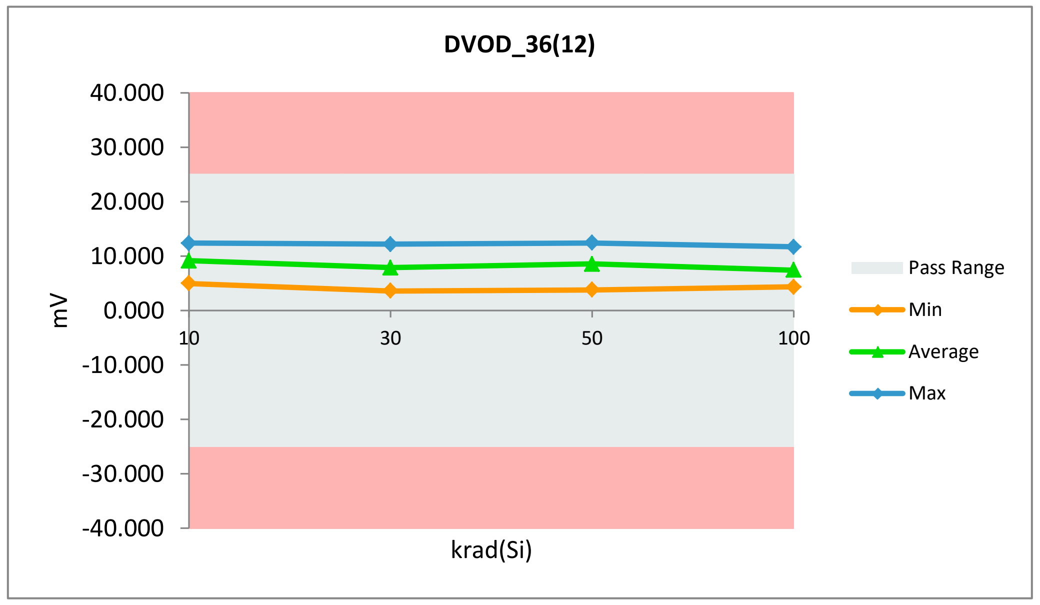
	DVOD_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	7.535	8.697	-1.162
10	5	8.758	8.694	0.064
10	7	6.315	7.474	-1.159
10	11	11.227	12.384	-1.158
10	15	9.985	12.376	-2.391
10	20	5.081	5.015	0.066
10	21	7.545	6.248	1.297
10	24	12.455	12.385	0.070
30	1	7.535	6.055	1.480
30	5	8.758	8.482	0.276
30	7	6.315	6.085	0.230
30	11	11.227	10.977	0.250
30	15	9.985	9.700	0.285
30	20	5.081	3.614	1.467
30	21	7.545	6.093	1.452
30	24	12.455	12.204	0.251
50	1	7.535	7.512	0.023
50	5	8.758	8.737	0.021
50	7	6.315	7.517	-1.202
50	11	11.227	11.200	0.027
50	15	9.985	11.192	-1.207
50	20	5.081	3.831	1.250
50	21	7.545	6.291	1.254
50	24	12.455	12.428	0.027
100	3	11.222	9.278	1.944
100	8	6.307	6.817	-0.510
100	12	11.229	9.311	1.918
100	13	13.675	11.714	1.961
100	16	6.308	4.374	1.934
100	17	8.765	5.604	3.161
100	18	7.538	6.794	0.744
100	19	7.536	5.599	1.937
	Max	13.675	12.428	3.161
	Average	8.728	8.271	0.456
	Min	5.081	3.614	-2.391
	Std Dev	2.426	2.750	1.234



	DVOD_36(12)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	5.015	3.614	3.831	4.374
Average	9.159	7.901	8.588	7.436
Max	12.385	12.204	12.428	11.714
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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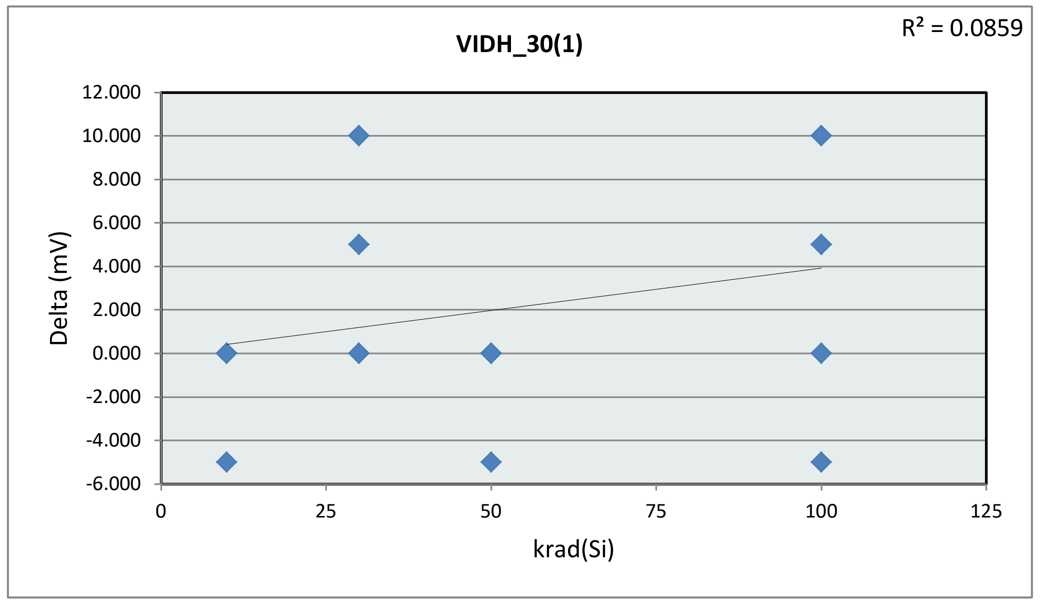
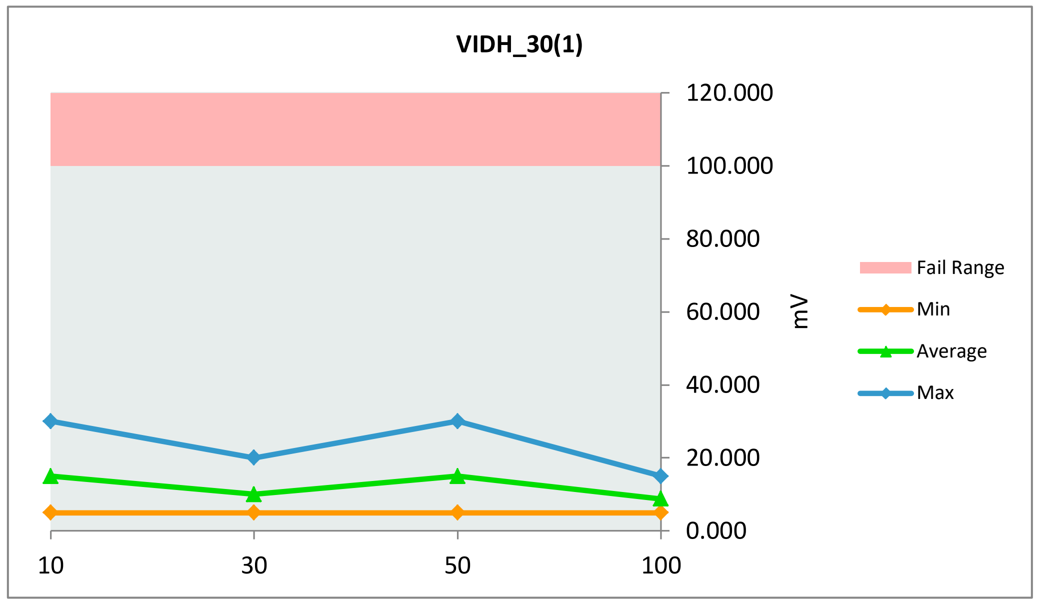
		VIDH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.000	5.000	0.000
10	5	5.000	5.000	0.000
10	7	5.000	5.000	0.000
10	11	30.000	30.000	0.000
10	15	5.000	5.000	0.000
10	20	30.000	30.000	0.000
10	21	15.000	20.000	-5.000
10	24	20.000	20.000	0.000
30	1	5.000	5.000	0.000
30	5	5.000	5.000	0.000
30	7	5.000	5.000	0.000
30	11	30.000	20.000	10.000
30	15	5.000	5.000	0.000
30	20	30.000	20.000	10.000
30	21	15.000	10.000	5.000
30	24	20.000	10.000	10.000
50	1	5.000	5.000	0.000
50	5	5.000	5.000	0.000
50	7	5.000	5.000	0.000
50	11	30.000	30.000	0.000
50	15	5.000	5.000	0.000
50	20	30.000	30.000	0.000
50	21	15.000	20.000	-5.000
50	24	20.000	20.000	0.000
100	3	20.000	10.000	10.000
100	8	5.000	5.000	0.000
100	12	5.000	10.000	-5.000
100	13	15.000	5.000	10.000
100	16	5.000	5.000	0.000
100	17	15.000	10.000	5.000
100	18	20.000	10.000	10.000
100	19	20.000	15.000	5.000
	Max	30.000	30.000	10.000
	Average	14.063	12.188	1.875
	Min	5.000	5.000	-5.000
	Std Dev	9.791	8.884	4.535

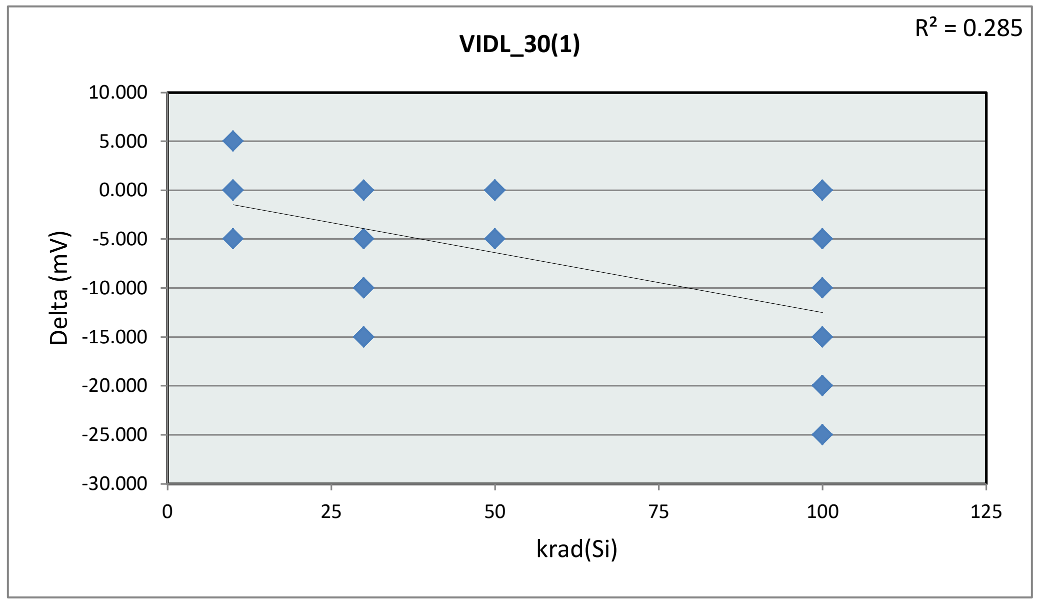


	VIDH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	15.000	10.000	15.000	8.750
Max	30.000	20.000	30.000	15.000
UL	100.000	100.000	100.000	100.000

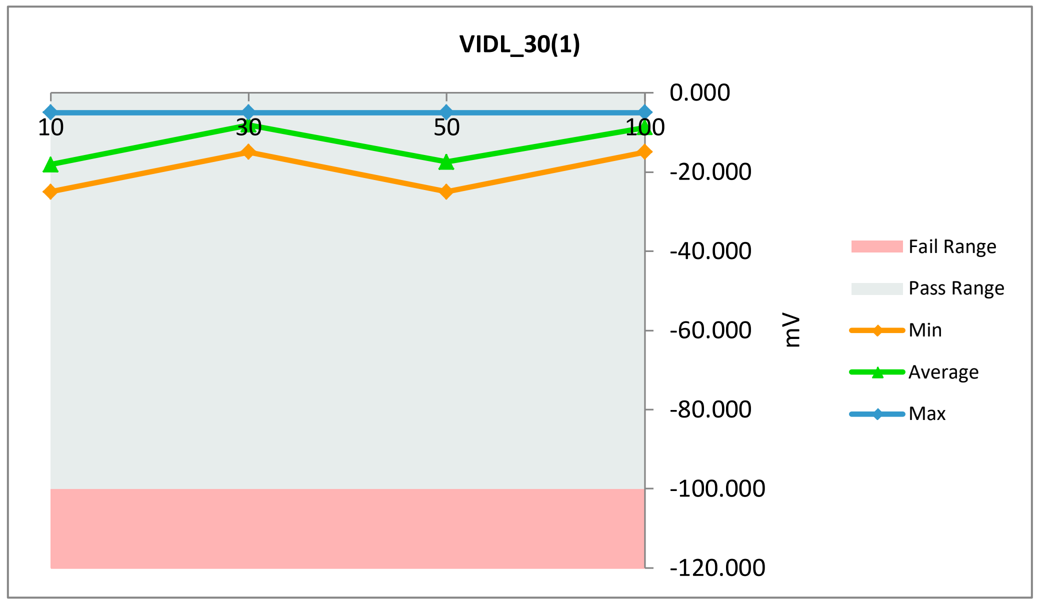


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-25.000	-25.000	0.000
10	5	-25.000	-25.000	0.000
10	7	-20.000	-15.000	-5.000
10	11	-20.000	-20.000	0.000
10	15	-15.000	-20.000	5.000
10	20	-10.000	-10.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-25.000	-25.000	0.000
30	1	-25.000	-10.000	-15.000
30	5	-25.000	-10.000	-15.000
30	7	-20.000	-5.000	-15.000
30	11	-20.000	-10.000	-10.000
30	15	-15.000	-5.000	-10.000
30	20	-10.000	-5.000	-5.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-15.000	-10.000
50	1	-25.000	-25.000	0.000
50	5	-25.000	-25.000	0.000
50	7	-20.000	-15.000	-5.000
50	11	-20.000	-20.000	0.000
50	15	-15.000	-15.000	0.000
50	20	-10.000	-10.000	0.000
50	21	-5.000	-5.000	0.000
50	24	-25.000	-25.000	0.000
100	3	-15.000	-5.000	-10.000
100	8	-35.000	-10.000	-25.000
100	12	-30.000	-10.000	-20.000
100	13	-30.000	-15.000	-15.000
100	16	-25.000	-5.000	-20.000
100	17	-5.000	-5.000	0.000
100	18	-15.000	-10.000	-5.000
100	19	-25.000	-10.000	-15.000
	Max	-5.000	-5.000	5.000
	Average	-19.219	-13.125	-6.094
	Min	-35.000	-25.000	-25.000
	Std Dev	8.043	7.378	7.801



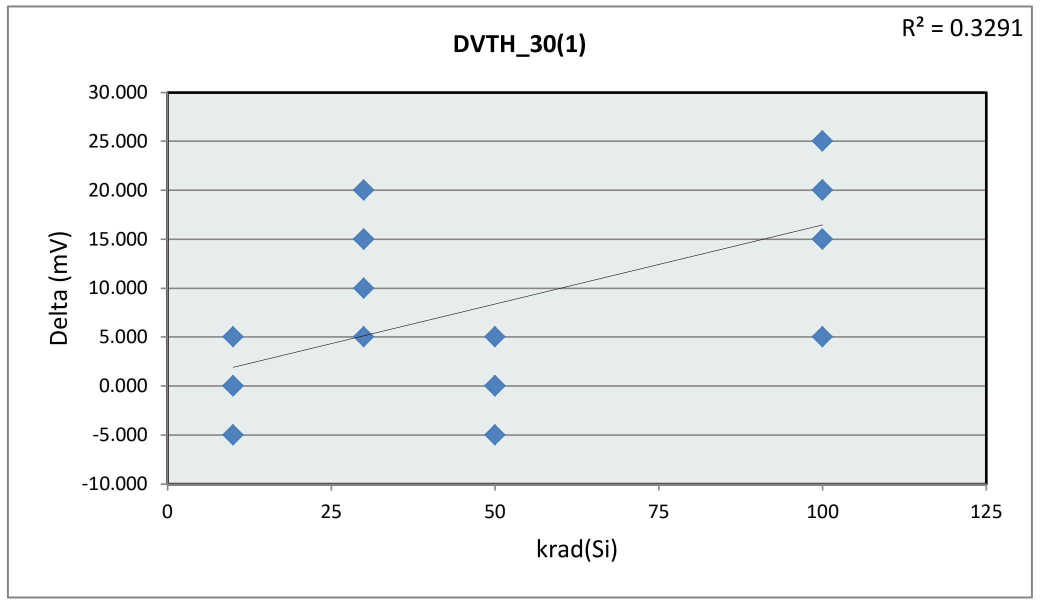
	VIDL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-15.000	-25.000	-15.000
Average	-18.125	-8.125	-17.500	-8.750
Max	-5.000	-5.000	-5.000	-5.000
UL				



LDR Biased TID Report
SN55LVCP22A-SP

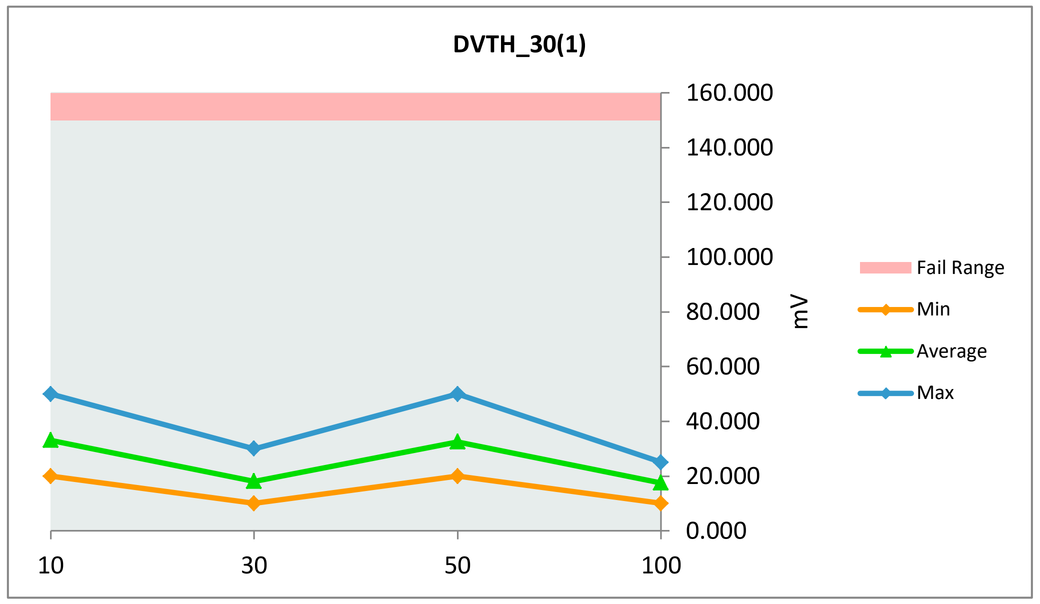
	DVTH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	30.000	30.000	0.000
10	5	30.000	30.000	0.000
10	7	25.000	20.000	5.000
10	11	50.000	50.000	0.000
10	15	20.000	25.000	-5.000
10	20	40.000	40.000	0.000
10	21	20.000	25.000	-5.000
10	24	45.000	45.000	0.000
30	1	30.000	15.000	15.000
30	5	30.000	15.000	15.000
30	7	25.000	10.000	15.000
30	11	50.000	30.000	20.000
30	15	20.000	10.000	10.000
30	20	40.000	25.000	15.000
30	21	20.000	15.000	5.000
30	24	45.000	25.000	20.000
50	1	30.000	30.000	0.000
50	5	30.000	30.000	0.000
50	7	25.000	20.000	5.000
50	11	50.000	50.000	0.000
50	15	20.000	20.000	0.000
50	20	40.000	40.000	0.000
50	21	20.000	25.000	-5.000
50	24	45.000	45.000	0.000
100	3	35.000	15.000	20.000
100	8	40.000	15.000	25.000
100	12	35.000	20.000	15.000
100	13	45.000	20.000	25.000
100	16	30.000	10.000	20.000
100	17	20.000	15.000	5.000
100	18	35.000	20.000	15.000
100	19	45.000	25.000	20.000
	Max	50.000	50.000	25.000
	Average	33.281	25.313	7.969
	Min	20.000	10.000	-5.000
	Std Dev	10.208	11.426	9.576



	DVTH_30(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	mV
Min Limit		mV

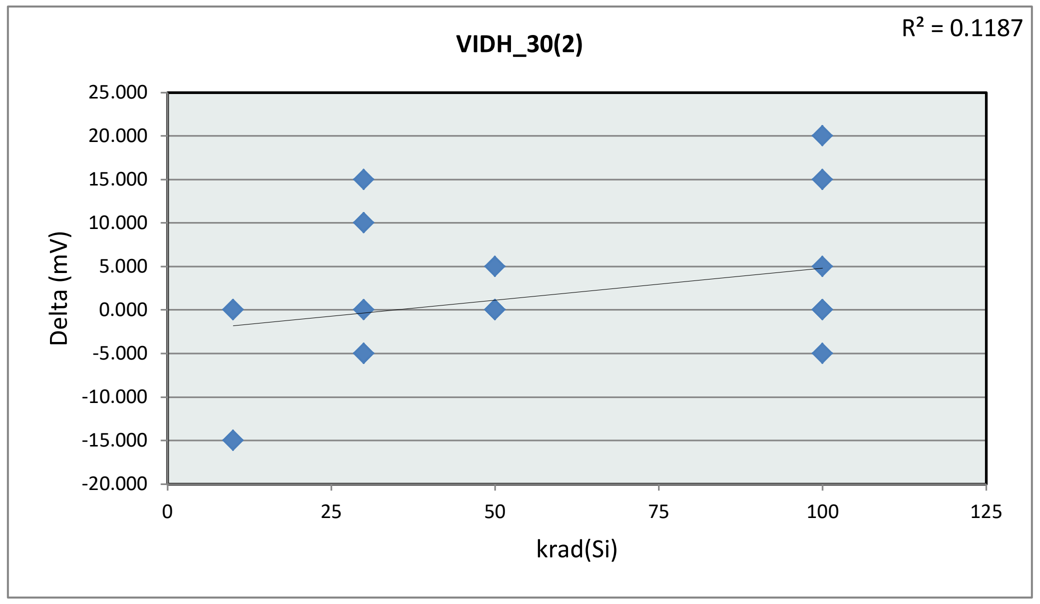
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	20.000	10.000
Average	33.125	18.125	32.500	17.500
Max	50.000	30.000	50.000	25.000
UL	150.000	150.000	150.000	150.000



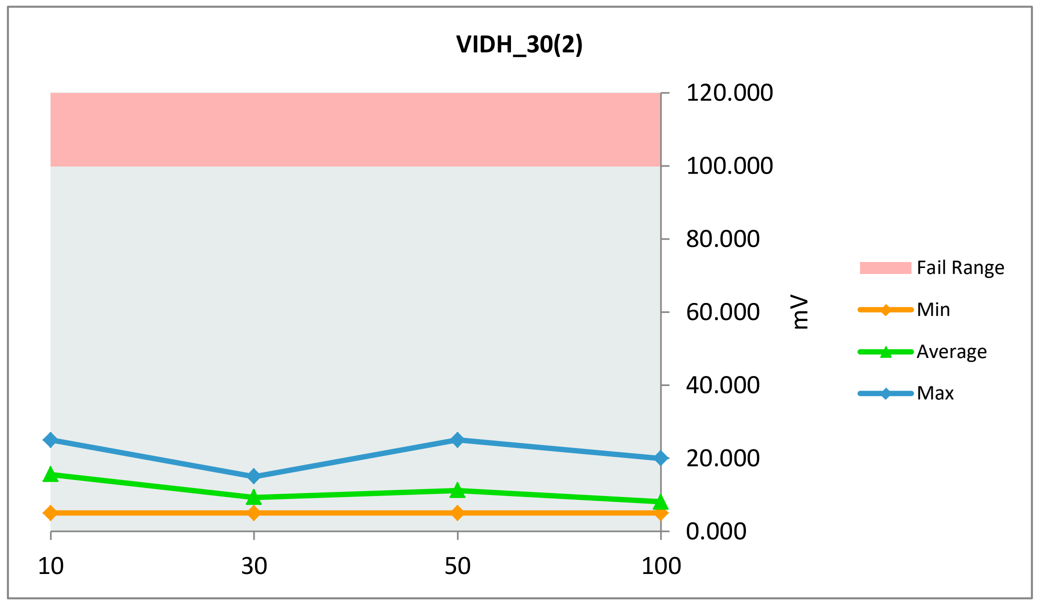
LDR Biased TID Report
SN55LVCP22A-SP

	VIDH_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	25.000	25.000	0.000
10	5	5.000	5.000	0.000
10	7	20.000	20.000	0.000
10	11	5.000	5.000	0.000
10	15	5.000	5.000	0.000
10	20	5.000	20.000	-15.000
10	21	25.000	25.000	0.000
10	24	5.000	20.000	-15.000
30	1	25.000	10.000	15.000
30	5	5.000	5.000	0.000
30	7	20.000	10.000	10.000
30	11	5.000	10.000	-5.000
30	15	5.000	5.000	0.000
30	20	5.000	10.000	-5.000
30	21	25.000	15.000	10.000
30	24	5.000	10.000	-5.000
50	1	25.000	25.000	0.000
50	5	5.000	5.000	0.000
50	7	20.000	20.000	0.000
50	11	5.000	5.000	0.000
50	15	5.000	5.000	0.000
50	20	5.000	5.000	0.000
50	21	25.000	20.000	5.000
50	24	5.000	5.000	0.000
100	3	5.000	5.000	0.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	30.000	10.000	20.000
100	16	5.000	5.000	0.000
100	17	20.000	5.000	15.000
100	18	25.000	20.000	5.000
100	19	5.000	10.000	-5.000
	Max	30.000	25.000	20.000
	Average	12.031	11.094	0.938
	Min	5.000	5.000	-15.000
	Std Dev	9.407	7.266	7.233

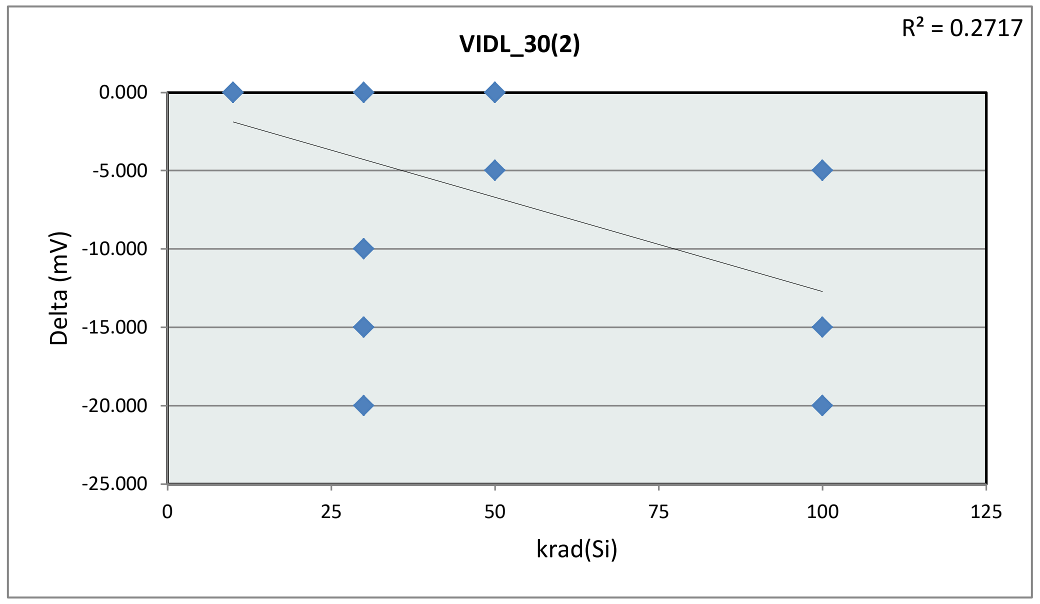


	VIDH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	15.625	9.375	11.250	8.125
Max	25.000	15.000	25.000	20.000
UL	100.000	100.000	100.000	100.000

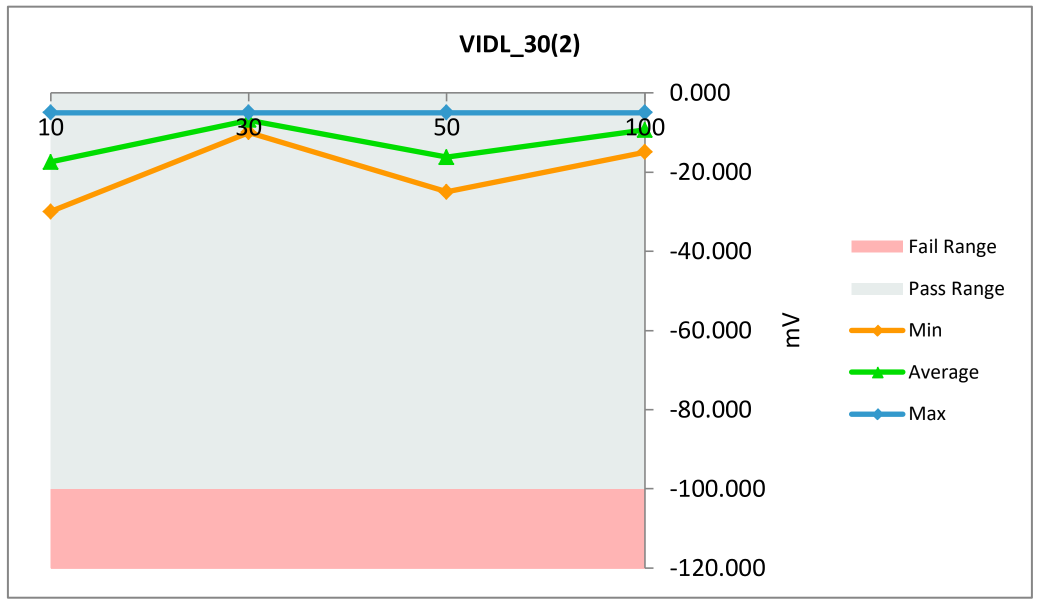


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-15.000	-15.000	0.000
10	5	-25.000	-25.000	0.000
10	7	-5.000	-5.000	0.000
10	11	-25.000	-25.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-20.000	-20.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-30.000	-30.000	0.000
30	1	-15.000	-5.000	-10.000
30	5	-25.000	-10.000	-15.000
30	7	-5.000	-5.000	0.000
30	11	-25.000	-10.000	-15.000
30	15	-15.000	-5.000	-10.000
30	20	-20.000	-5.000	-15.000
30	21	-5.000	-5.000	0.000
30	24	-30.000	-10.000	-20.000
50	1	-15.000	-15.000	0.000
50	5	-25.000	-25.000	0.000
50	7	-5.000	-5.000	0.000
50	11	-25.000	-20.000	-5.000
50	15	-15.000	-15.000	0.000
50	20	-20.000	-20.000	0.000
50	21	-5.000	-5.000	0.000
50	24	-30.000	-25.000	-5.000
100	3	-30.000	-15.000	-15.000
100	8	-35.000	-15.000	-20.000
100	12	-30.000	-10.000	-20.000
100	13	-25.000	-5.000	-20.000
100	16	-15.000	-10.000	-5.000
100	17	-10.000	-5.000	-5.000
100	18	-10.000	-5.000	-5.000
100	19	-30.000	-10.000	-20.000
	Max	-5.000	-5.000	0.000
	Average	-18.906	-12.500	-6.406
	Min	-35.000	-30.000	-20.000
	Std Dev	9.310	7.725	7.853

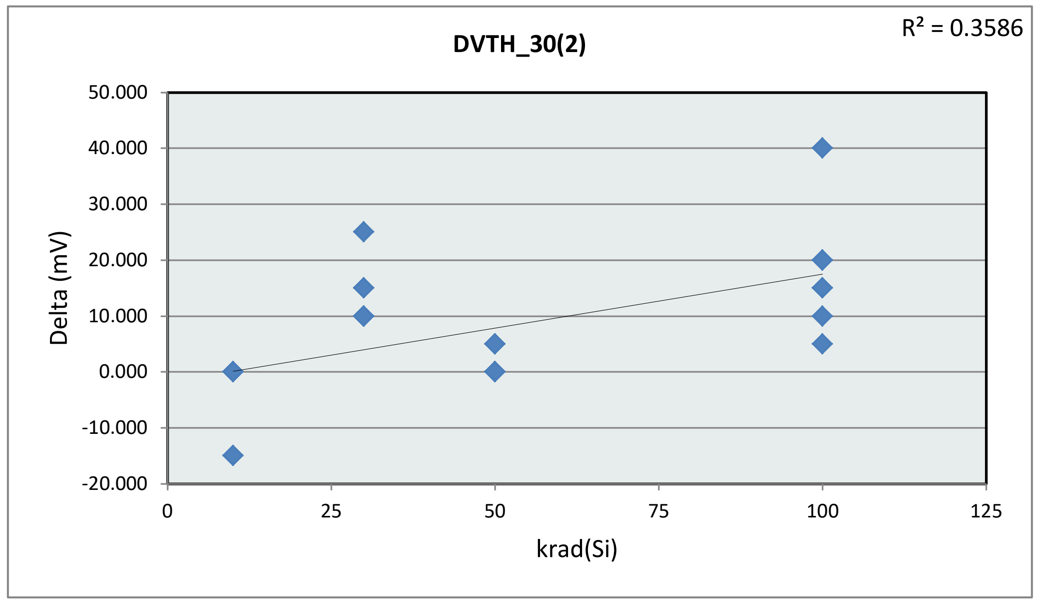


	VIDL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-30.000	-10.000	-25.000	-15.000
Average	-17.500	-6.875	-16.250	-9.375
Max	-5.000	-5.000	-5.000	-5.000
UL				

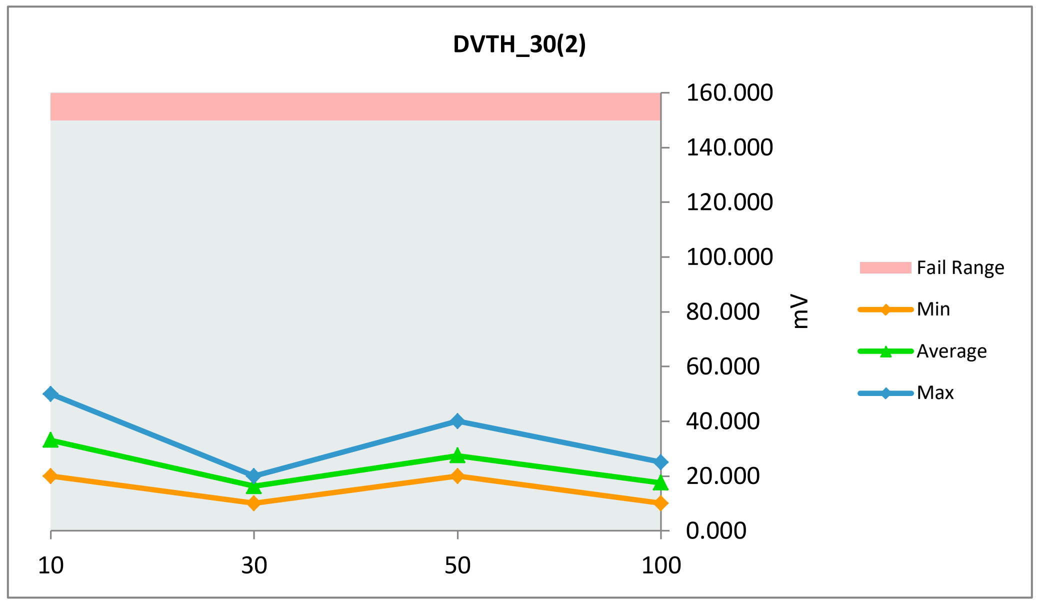


LDR Biased TID Report
SN55LVCP22A-SP

		DVTH_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		150	150	
Min Limit				
krad(Si)	**Serial #**	**LDR Pre Test**	**LDR Post Test**	**Delta**
10	1	40.000	40.000	0.000
10	5	30.000	30.000	0.000
10	7	25.000	25.000	0.000
10	11	30.000	30.000	0.000
10	15	20.000	20.000	0.000
10	20	25.000	40.000	-15.000
10	21	30.000	30.000	0.000
10	24	35.000	50.000	-15.000
30	1	40.000	15.000	25.000
30	5	30.000	15.000	15.000
30	7	25.000	15.000	10.000
30	11	30.000	20.000	10.000
30	15	20.000	10.000	10.000
30	20	25.000	15.000	10.000
30	21	30.000	20.000	10.000
30	24	35.000	20.000	15.000
50	1	40.000	40.000	0.000
50	5	30.000	30.000	0.000
50	7	25.000	25.000	0.000
50	11	30.000	25.000	5.000
50	15	20.000	20.000	0.000
50	20	25.000	25.000	0.000
50	21	30.000	25.000	5.000
50	24	35.000	30.000	5.000
100	3	35.000	20.000	15.000
100	8	40.000	20.000	20.000
100	12	35.000	15.000	20.000
100	13	55.000	15.000	40.000
100	16	20.000	15.000	5.000
100	17	30.000	10.000	20.000
100	18	35.000	25.000	10.000
100	19	35.000	20.000	15.000
	Max	55.000	50.000	40.000
	Average	30.938	23.594	7.344
	Min	20.000	10.000	-15.000
	Std Dev	7.453	9.353	10.997



	DVTH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	**10**	**30**	**50**	**100**
LL				
Min	20.000	10.000	20.000	10.000
Average	33.125	16.250	27.500	17.500
Max	50.000	20.000	40.000	25.000
UL	150.000	150.000	150.000	150.000



LDR Biased TID Report
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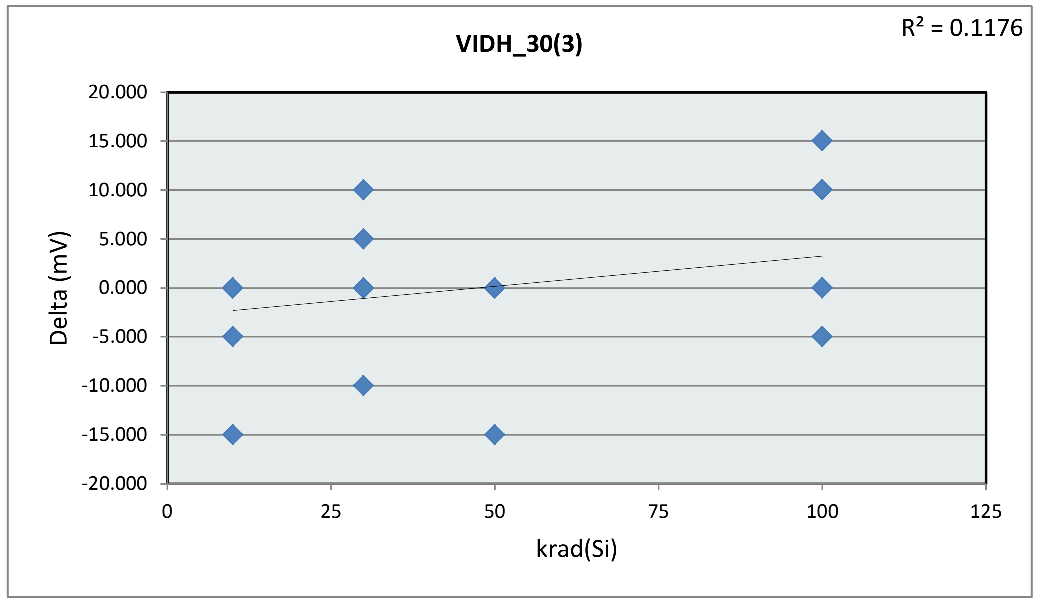
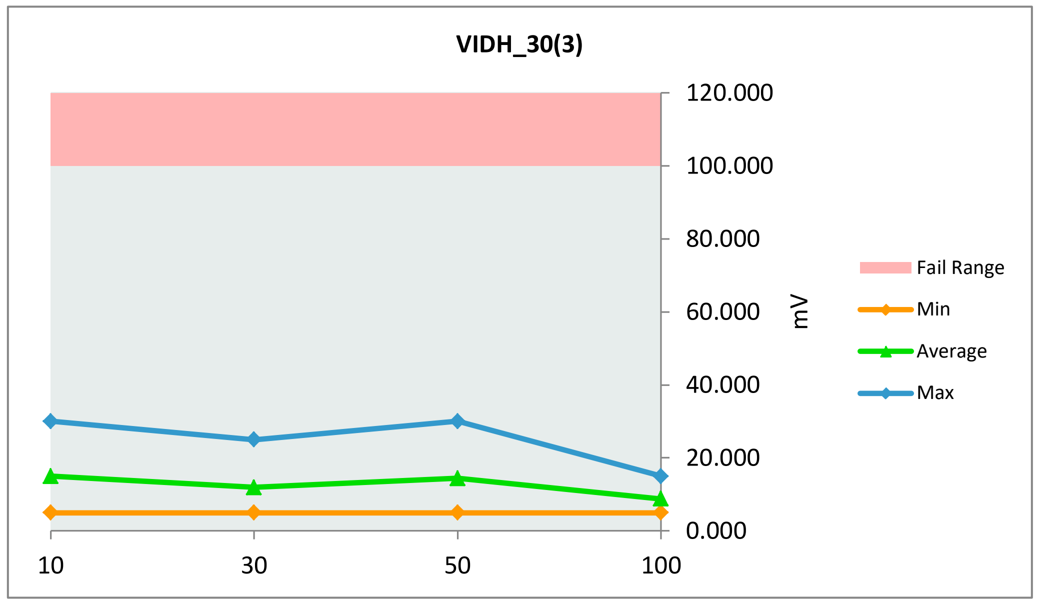
	VIDH_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.000	5.000	0.000
10	5	5.000	5.000	0.000
10	7	5.000	5.000	0.000
10	11	25.000	30.000	-5.000
10	15	5.000	5.000	0.000
10	20	30.000	30.000	0.000
10	21	5.000	20.000	-15.000
10	24	20.000	20.000	0.000
30	1	5.000	5.000	0.000
30	5	5.000	5.000	0.000
30	7	5.000	5.000	0.000
30	11	25.000	25.000	0.000
30	15	5.000	5.000	0.000
30	20	30.000	20.000	10.000
30	21	5.000	15.000	-10.000
30	24	20.000	15.000	5.000
50	1	5.000	5.000	0.000
50	5	5.000	5.000	0.000
50	7	5.000	5.000	0.000
50	11	25.000	25.000	0.000
50	15	5.000	5.000	0.000
50	20	30.000	30.000	0.000
50	21	5.000	20.000	-15.000
50	24	20.000	20.000	0.000
100	3	20.000	10.000	10.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	5.000	10.000	-5.000
100	16	5.000	5.000	0.000
100	17	15.000	15.000	0.000
100	18	20.000	10.000	10.000
100	19	25.000	10.000	15.000
	Max	30.000	30.000	15.000
	Average	12.500	12.500	0.000
	Min	5.000	5.000	-15.000
	Std Dev	9.672	8.799	6.091



	VIDH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	15.000	11.875	14.375	8.750
Max	30.000	25.000	30.000	15.000
UL	100.000	100.000	100.000	100.000



LDR Biased TID Report
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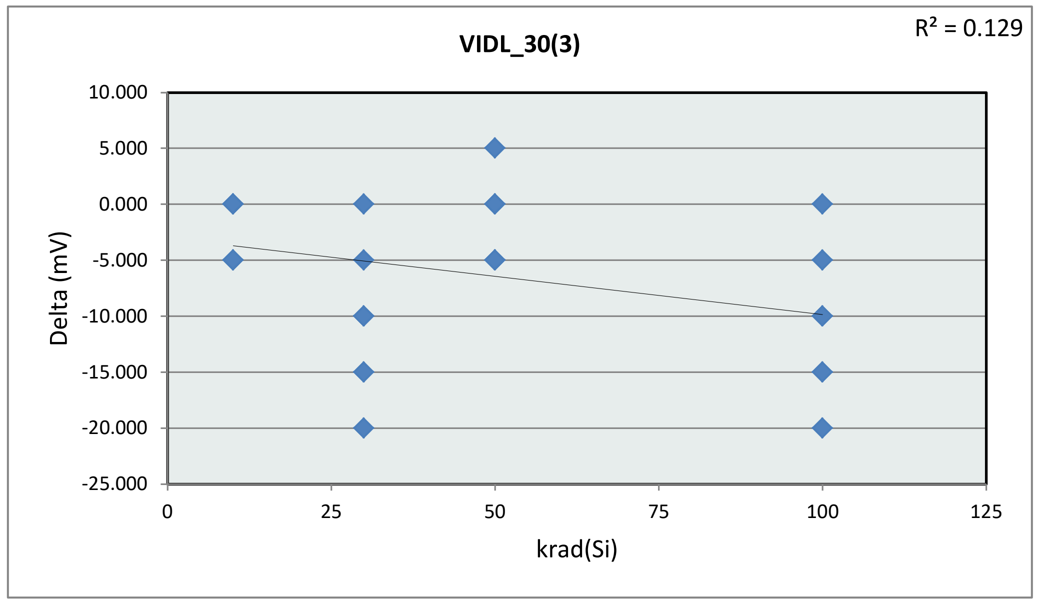
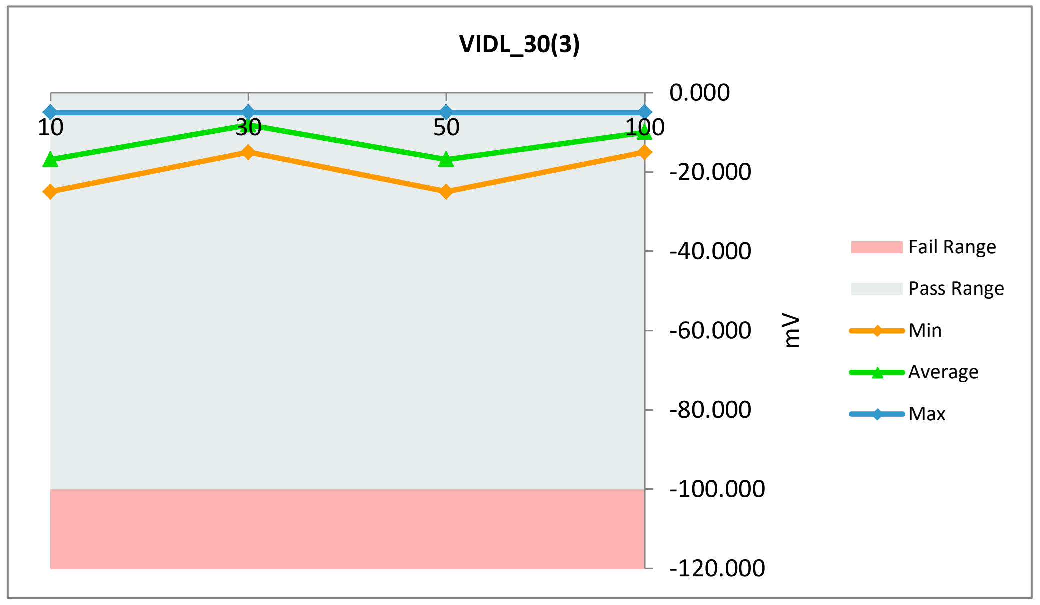
	VIDL_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-30.000	-25.000	-5.000
10	5	-25.000	-25.000	0.000
10	7	-20.000	-15.000	-5.000
10	11	-20.000	-20.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-5.000	-5.000	0.000
10	21	-10.000	-5.000	-5.000
10	24	-25.000	-25.000	0.000
30	1	-30.000	-10.000	-20.000
30	5	-25.000	-10.000	-15.000
30	7	-20.000	-5.000	-15.000
30	11	-20.000	-10.000	-10.000
30	15	-15.000	-5.000	-10.000
30	20	-5.000	-5.000	0.000
30	21	-10.000	-5.000	-5.000
30	24	-25.000	-15.000	-10.000
50	1	-30.000	-25.000	-5.000
50	5	-25.000	-20.000	-5.000
50	7	-20.000	-15.000	-5.000
50	11	-20.000	-20.000	0.000
50	15	-15.000	-15.000	0.000
50	20	-5.000	-10.000	5.000
50	21	-10.000	-5.000	-5.000
50	24	-25.000	-25.000	0.000
100	3	-15.000	-5.000	-10.000
100	8	-30.000	-15.000	-15.000
100	12	-25.000	-10.000	-15.000
100	13	-30.000	-10.000	-20.000
100	16	-20.000	-10.000	-10.000
100	17	-5.000	-5.000	0.000
100	18	-15.000	-10.000	-5.000
100	19	-25.000	-15.000	-10.000
	Max	-5.000	-5.000	5.000
	Average	-19.219	-12.969	-6.250
	Min	-30.000	-25.000	-20.000
	Std Dev	8.043	7.055	6.476



	VIDL_30(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit		mV
Min Limit	-100	mV

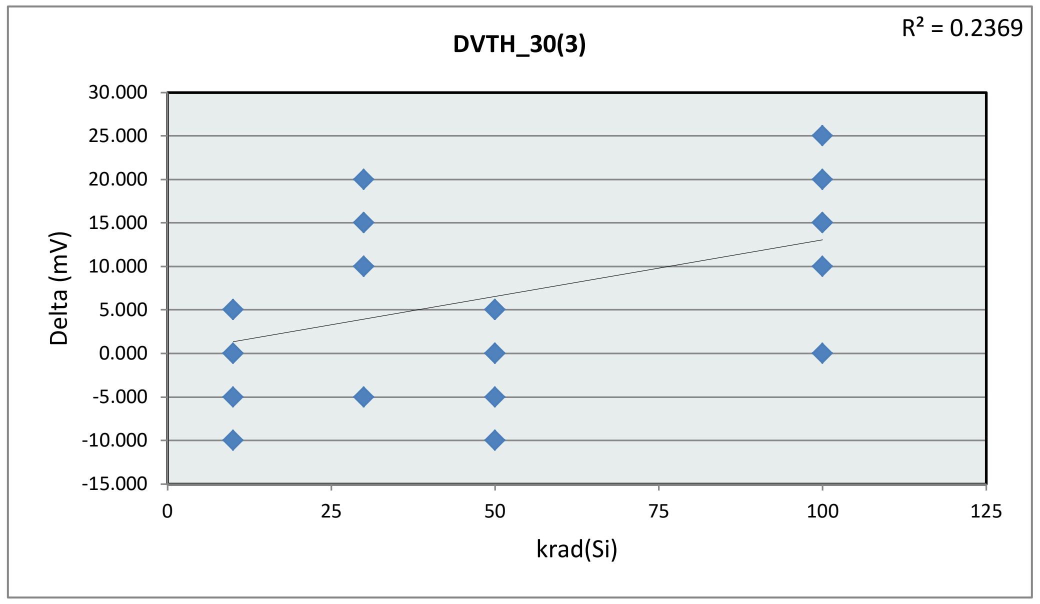
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-15.000	-25.000	-15.000
Average	-16.875	-8.125	-16.875	-10.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



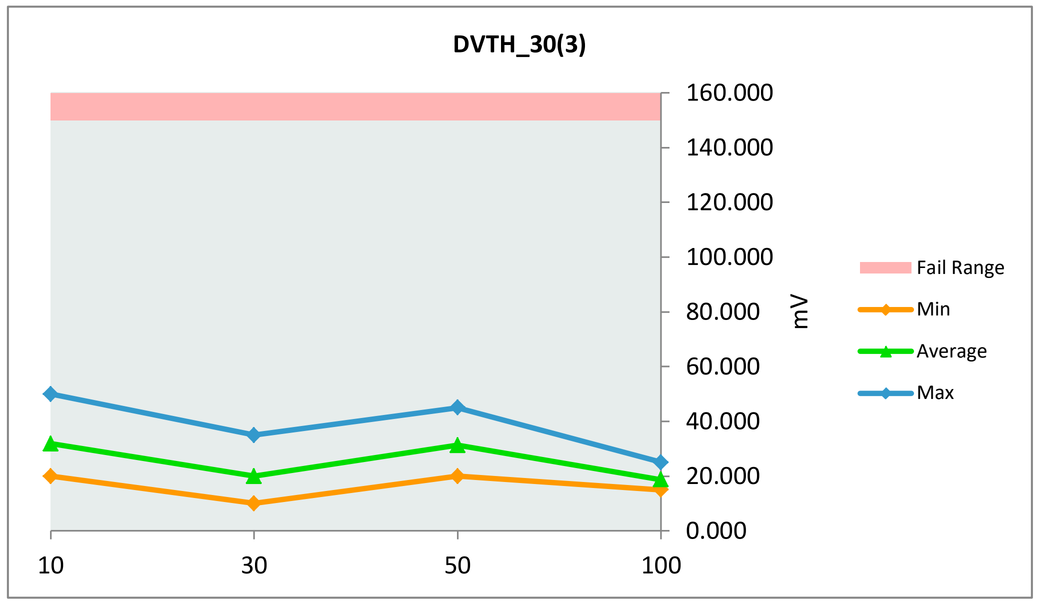
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	35.000	30.000	5.000
10	5	30.000	30.000	0.000
10	7	25.000	20.000	5.000
10	11	45.000	50.000	-5.000
10	15	20.000	20.000	0.000
10	20	35.000	35.000	0.000
10	21	15.000	25.000	-10.000
10	24	45.000	45.000	0.000
30	1	35.000	15.000	20.000
30	5	30.000	15.000	15.000
30	7	25.000	10.000	15.000
30	11	45.000	35.000	10.000
30	15	20.000	10.000	10.000
30	20	35.000	25.000	10.000
30	21	15.000	20.000	-5.000
30	24	45.000	30.000	15.000
50	1	35.000	30.000	5.000
50	5	30.000	25.000	5.000
50	7	25.000	20.000	5.000
50	11	45.000	45.000	0.000
50	15	20.000	20.000	0.000
50	20	35.000	40.000	-5.000
50	21	15.000	25.000	-10.000
50	24	45.000	45.000	0.000
100	3	35.000	15.000	20.000
100	8	35.000	20.000	15.000
100	12	30.000	15.000	15.000
100	13	35.000	20.000	15.000
100	16	25.000	15.000	10.000
100	17	20.000	20.000	0.000
100	18	35.000	20.000	15.000
100	19	50.000	25.000	25.000
	Max	50.000	50.000	25.000
	Average	31.719	25.469	6.250
	Min	15.000	10.000	-10.000
	Std Dev	9.968	10.653	9.070



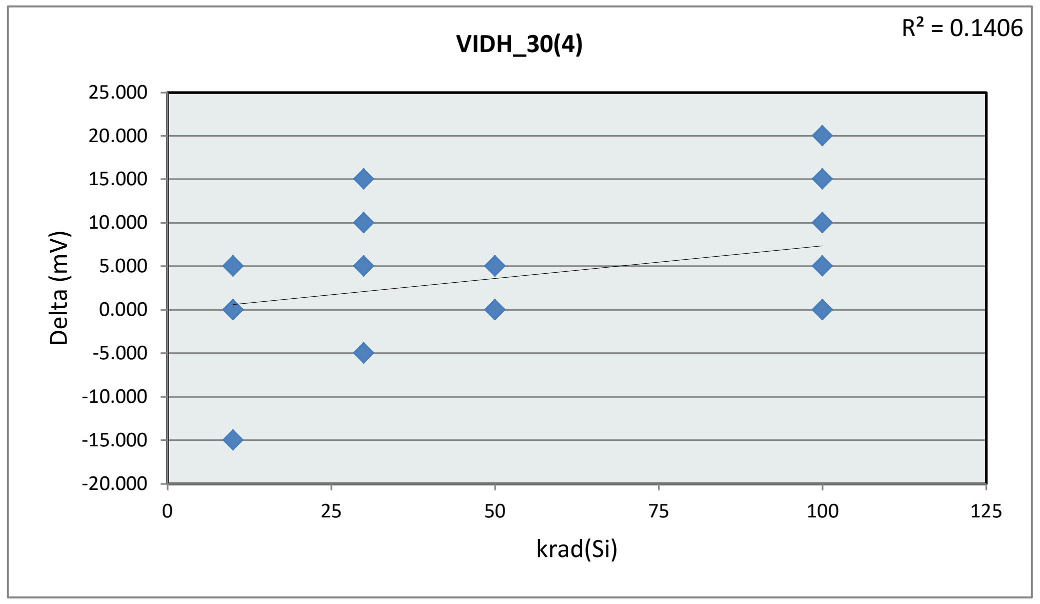
	DVTH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	20.000	15.000
Average	31.875	20.000	31.250	18.750
Max	50.000	35.000	45.000	25.000
UL	150.000	150.000	150.000	150.000



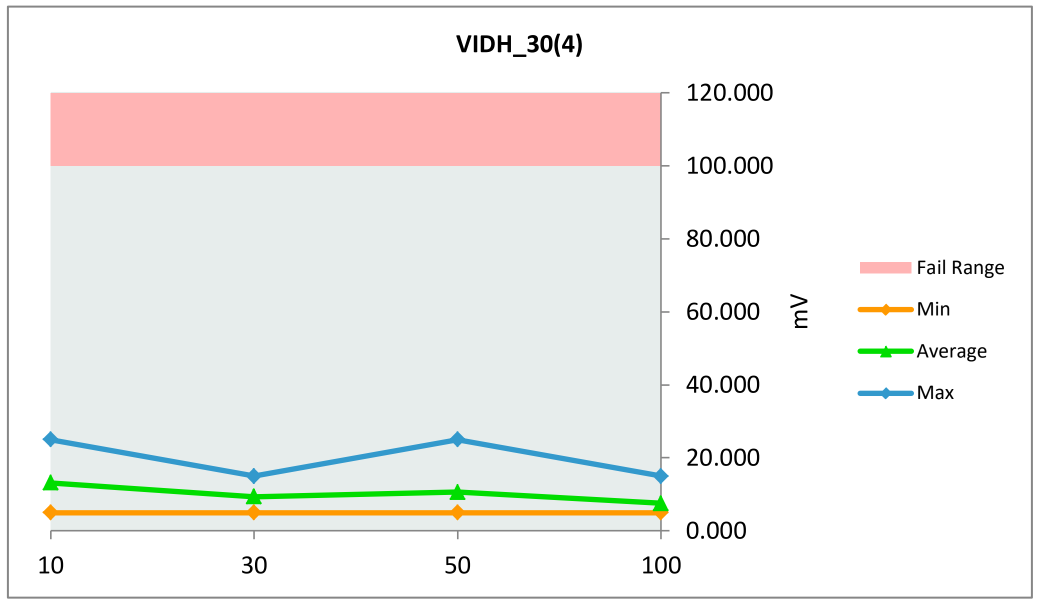
LDR Biased TID Report
SN55LVCP22A-SP

	VIDH_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	25.000	25.000	0.000
10	5	10.000	5.000	5.000
10	7	20.000	20.000	0.000
10	11	5.000	5.000	0.000
10	15	10.000	5.000	5.000
10	20	5.000	5.000	0.000
10	21	25.000	20.000	5.000
10	24	5.000	20.000	-15.000
30	1	25.000	15.000	10.000
30	5	10.000	5.000	5.000
30	7	20.000	10.000	10.000
30	11	5.000	10.000	-5.000
30	15	10.000	5.000	5.000
30	20	5.000	10.000	-5.000
30	21	25.000	10.000	15.000
30	24	5.000	10.000	-5.000
50	1	25.000	25.000	0.000
50	5	10.000	5.000	5.000
50	7	20.000	15.000	5.000
50	11	5.000	5.000	0.000
50	15	10.000	5.000	5.000
50	20	5.000	5.000	0.000
50	21	25.000	20.000	5.000
50	24	5.000	5.000	0.000
100	3	15.000	5.000	10.000
100	8	5.000	5.000	0.000
100	12	15.000	5.000	10.000
100	13	30.000	10.000	20.000
100	16	5.000	5.000	0.000
100	17	20.000	15.000	5.000
100	18	25.000	10.000	15.000
100	19	5.000	5.000	0.000
	Max	30.000	25.000	20.000
	Average	13.594	10.156	3.438
	Min	5.000	5.000	-15.000
	Std Dev	8.635	6.536	6.773

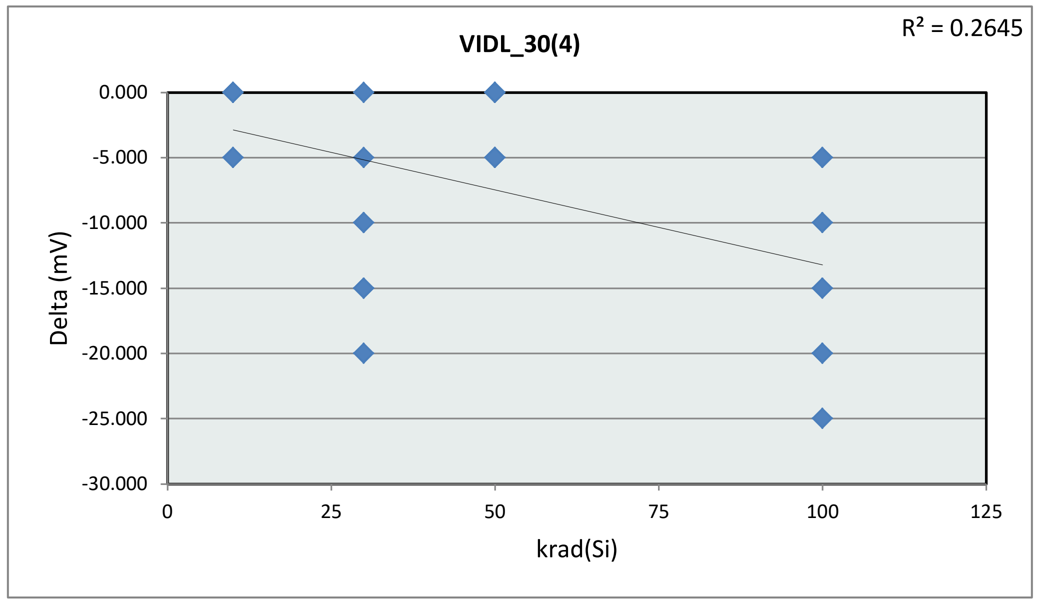


	VIDH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	13.125	9.375	10.625	7.500
Max	25.000	15.000	25.000	15.000
UL	100.000	100.000	100.000	100.000

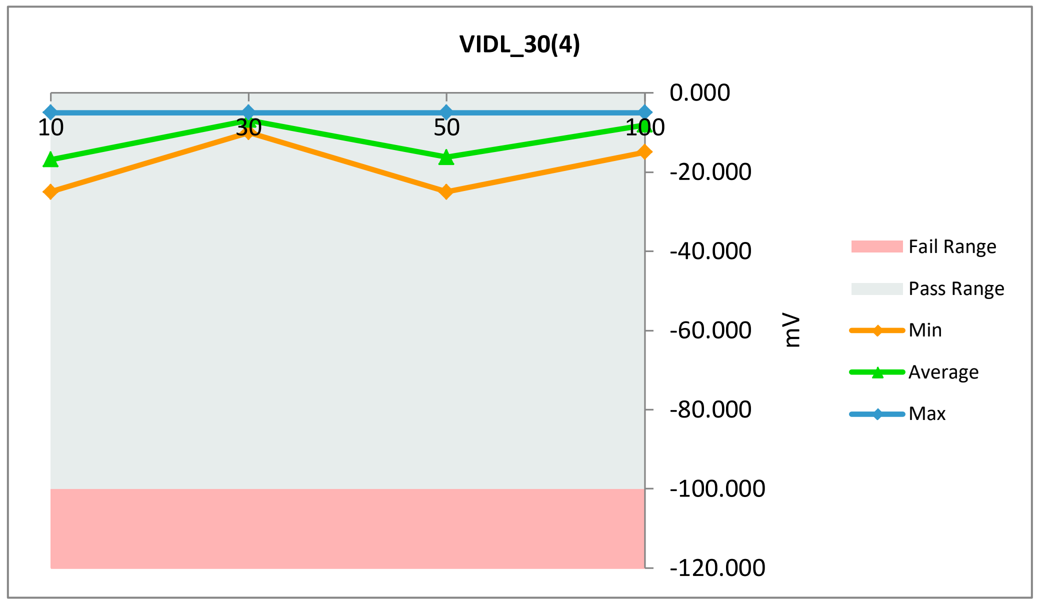


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_30(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-15.000	-15.000	0.000
10	5	-25.000	-25.000	0.000
10	7	-5.000	-5.000	0.000
10	11	-25.000	-25.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-20.000	-20.000	0.000
10	21	-10.000	-5.000	-5.000
10	24	-30.000	-25.000	-5.000
30	1	-15.000	-5.000	-10.000
30	5	-25.000	-10.000	-15.000
30	7	-5.000	-5.000	0.000
30	11	-25.000	-10.000	-15.000
30	15	-15.000	-5.000	-10.000
30	20	-20.000	-5.000	-15.000
30	21	-10.000	-5.000	-5.000
30	24	-30.000	-10.000	-20.000
50	1	-15.000	-15.000	0.000
50	5	-25.000	-25.000	0.000
50	7	-5.000	-5.000	0.000
50	11	-25.000	-20.000	-5.000
50	15	-15.000	-15.000	0.000
50	20	-20.000	-20.000	0.000
50	21	-10.000	-5.000	-5.000
50	24	-30.000	-25.000	-5.000
100	3	-30.000	-5.000	-25.000
100	8	-35.000	-15.000	-20.000
100	12	-25.000	-5.000	-20.000
100	13	-20.000	-5.000	-15.000
100	16	-20.000	-10.000	-10.000
100	17	-10.000	-5.000	-5.000
100	18	-10.000	-5.000	-5.000
100	19	-30.000	-15.000	-15.000
	Max	-5.000	-5.000	0.000
	Average	-19.219	-12.031	-7.188
	Min	-35.000	-25.000	-25.000
	Std Dev	8.435	7.605	7.613



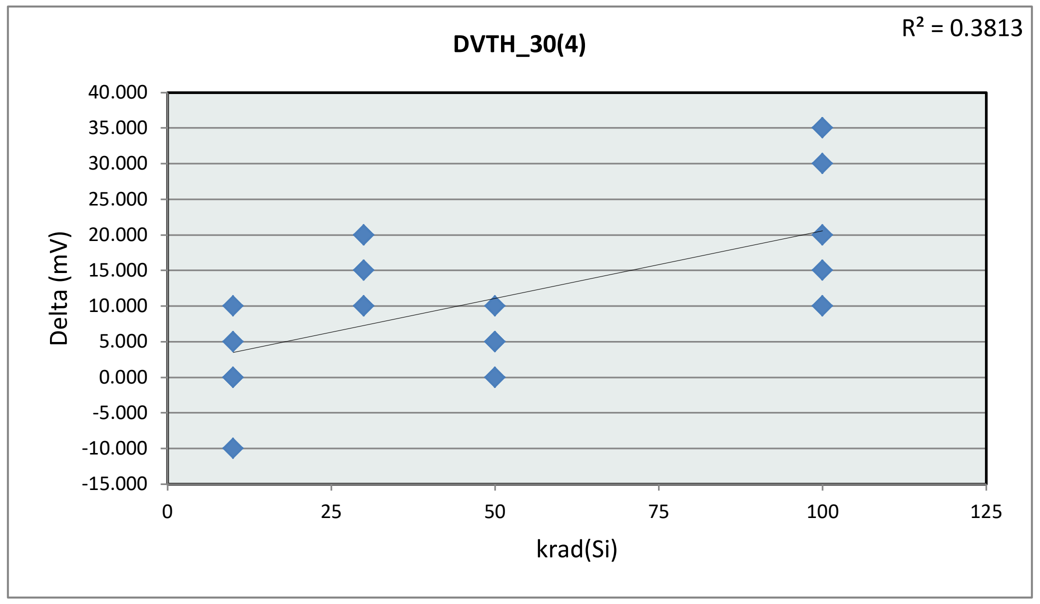
	VIDL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-10.000	-25.000	-15.000
Average	-16.875	-6.875	-16.250	-8.125
Max	-5.000	-5.000	-5.000	-5.000
UL				



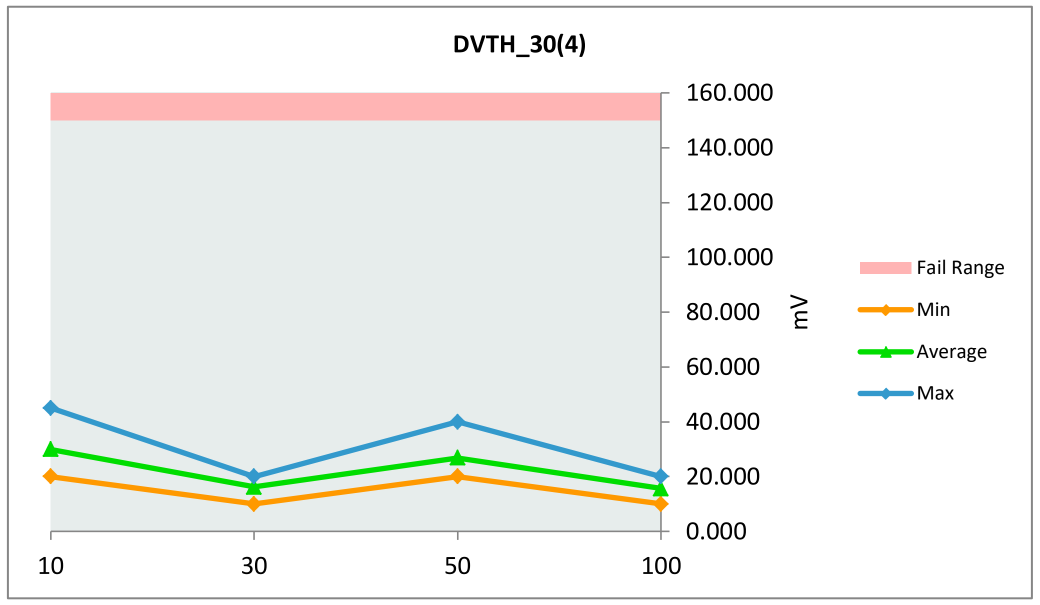
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_30(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	40.000	40.000	0.000
10	5	35.000	30.000	5.000
10	7	25.000	25.000	0.000
10	11	30.000	30.000	0.000
10	15	25.000	20.000	5.000
10	20	25.000	25.000	0.000
10	21	35.000	25.000	10.000
10	24	35.000	45.000	-10.000
30	1	40.000	20.000	20.000
30	5	35.000	15.000	20.000
30	7	25.000	15.000	10.000
30	11	30.000	20.000	10.000
30	15	25.000	10.000	15.000
30	20	25.000	15.000	10.000
30	21	35.000	15.000	20.000
30	24	35.000	20.000	15.000
50	1	40.000	40.000	0.000
50	5	35.000	30.000	5.000
50	7	25.000	20.000	5.000
50	11	30.000	25.000	5.000
50	15	25.000	20.000	5.000
50	20	25.000	25.000	0.000
50	21	35.000	25.000	10.000
50	24	35.000	30.000	5.000
100	3	45.000	10.000	35.000
100	8	40.000	20.000	20.000
100	12	40.000	10.000	30.000
100	13	50.000	15.000	35.000
100	16	25.000	15.000	10.000
100	17	30.000	20.000	10.000
100	18	35.000	15.000	20.000
100	19	35.000	20.000	15.000
	Max	50.000	45.000	35.000
	Average	32.813	22.188	10.625
	Min	25.000	10.000	-10.000
	Std Dev	6.713	8.608	10.453

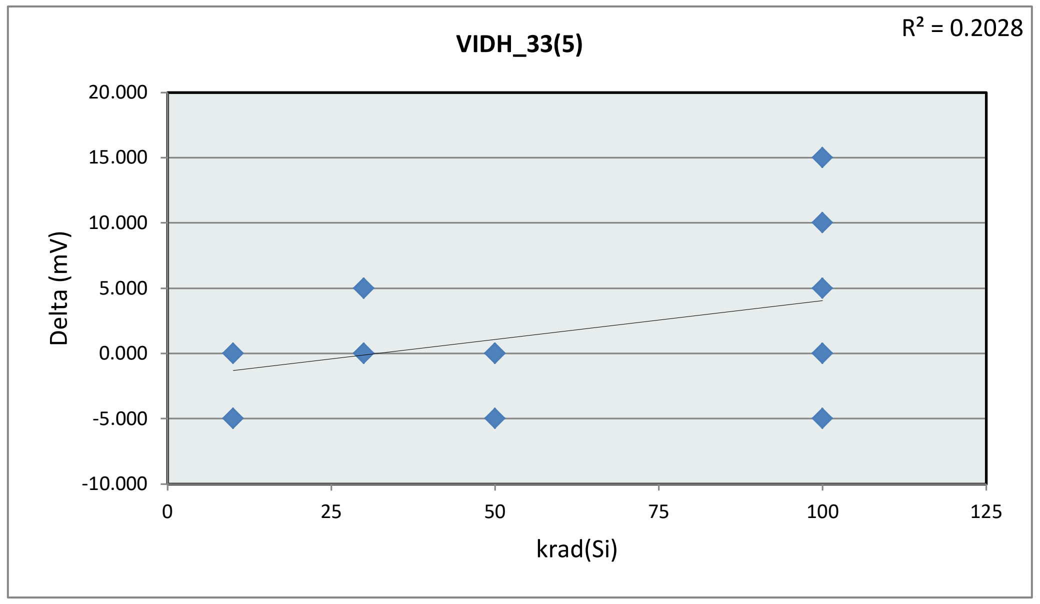


	DVTH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	20.000	10.000
Average	30.000	16.250	26.875	15.625
Max	45.000	20.000	40.000	20.000
UL	150.000	150.000	150.000	150.000

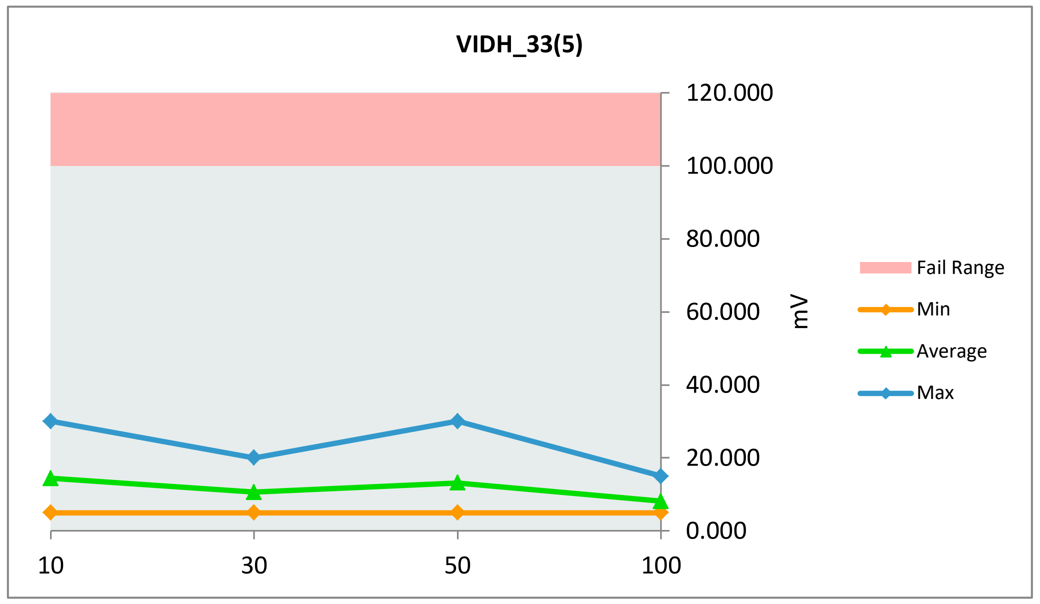


LDR Biased TID Report
SN55LVCP22A-SP

		VIDH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.000	5.000	0.000
10	5	5.000	5.000	0.000
10	7	5.000	5.000	0.000
10	11	25.000	30.000	-5.000
10	15	5.000	5.000	0.000
10	20	25.000	30.000	-5.000
10	21	15.000	15.000	0.000
10	24	15.000	20.000	-5.000
30	1	5.000	5.000	0.000
30	5	5.000	5.000	0.000
30	7	5.000	5.000	0.000
30	11	25.000	20.000	5.000
30	15	5.000	5.000	0.000
30	20	25.000	20.000	5.000
30	21	15.000	10.000	5.000
30	24	15.000	15.000	0.000
50	1	5.000	5.000	0.000
50	5	5.000	5.000	0.000
50	7	5.000	5.000	0.000
50	11	25.000	25.000	0.000
50	15	5.000	5.000	0.000
50	20	25.000	30.000	-5.000
50	21	15.000	15.000	0.000
50	24	15.000	15.000	0.000
100	3	20.000	10.000	10.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	15.000	10.000	5.000
100	16	5.000	5.000	0.000
100	17	10.000	15.000	-5.000
100	18	20.000	5.000	15.000
100	19	20.000	10.000	10.000
	Max	25.000	30.000	15.000
	Average	12.500	11.563	0.938
	Min	5.000	5.000	-5.000
	Std Dev	8.032	8.370	4.479



	VIDH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	14.375	10.625	13.125	8.125
Max	30.000	20.000	30.000	15.000
UL	100.000	100.000	100.000	100.000



LDR Biased TID Report
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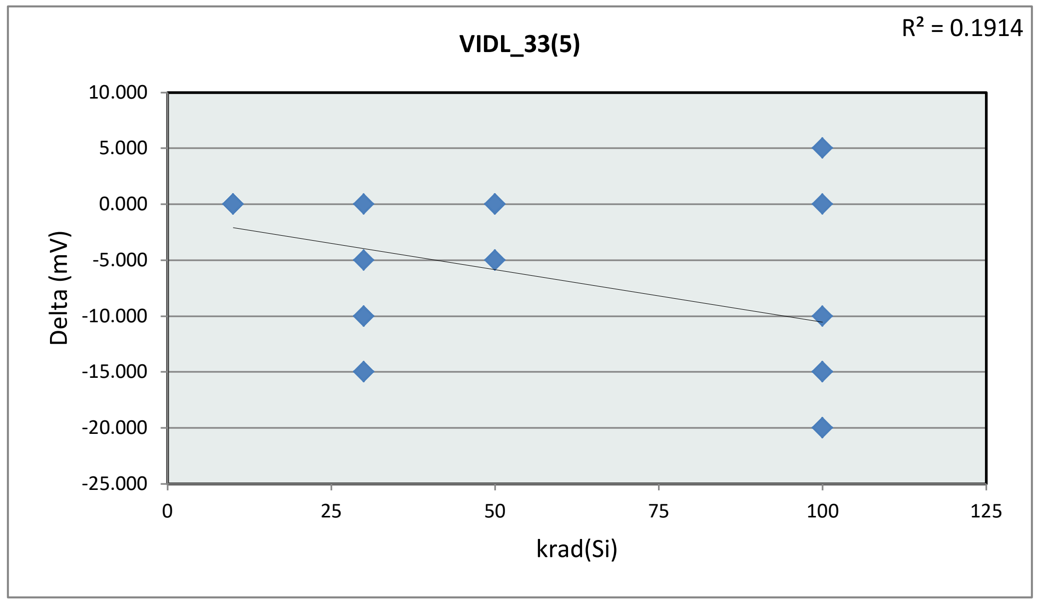
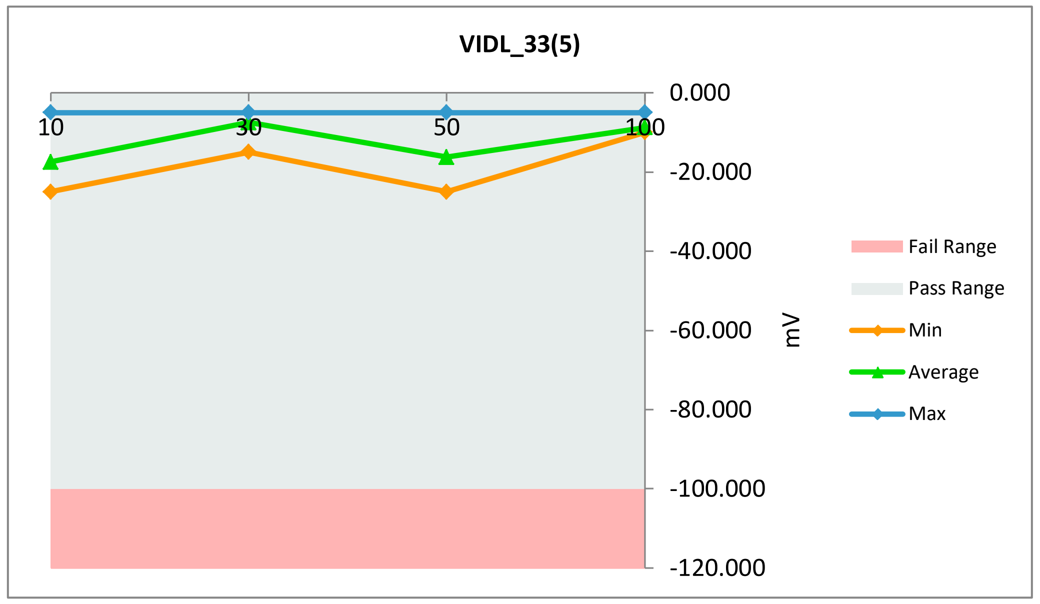
	VIDL_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-25.000	-25.000	0.000
10	5	-25.000	-25.000	0.000
10	7	-15.000	-15.000	0.000
10	11	-20.000	-20.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-10.000	-10.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-25.000	-25.000	0.000
30	1	-25.000	-15.000	-10.000
30	5	-25.000	-10.000	-15.000
30	7	-15.000	-5.000	-10.000
30	11	-20.000	-5.000	-15.000
30	15	-15.000	-5.000	-10.000
30	20	-10.000	-5.000	-5.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-10.000	-15.000
50	1	-25.000	-25.000	0.000
50	5	-25.000	-20.000	-5.000
50	7	-15.000	-15.000	0.000
50	11	-20.000	-20.000	0.000
50	15	-15.000	-15.000	0.000
50	20	-10.000	-5.000	-5.000
50	21	-5.000	-5.000	0.000
50	24	-25.000	-25.000	0.000
100	3	-15.000	-5.000	-10.000
100	8	-30.000	-10.000	-20.000
100	12	-25.000	-10.000	-15.000
100	13	-30.000	-10.000	-20.000
100	16	-25.000	-10.000	-15.000
100	17	-5.000	-5.000	0.000
100	18	-5.000	-10.000	5.000
100	19	-25.000	-10.000	-15.000
	Max	-5.000	-5.000	5.000
	Average	-18.125	-12.500	-5.625
	Min	-30.000	-25.000	-20.000
	Std Dev	8.007	7.184	7.268



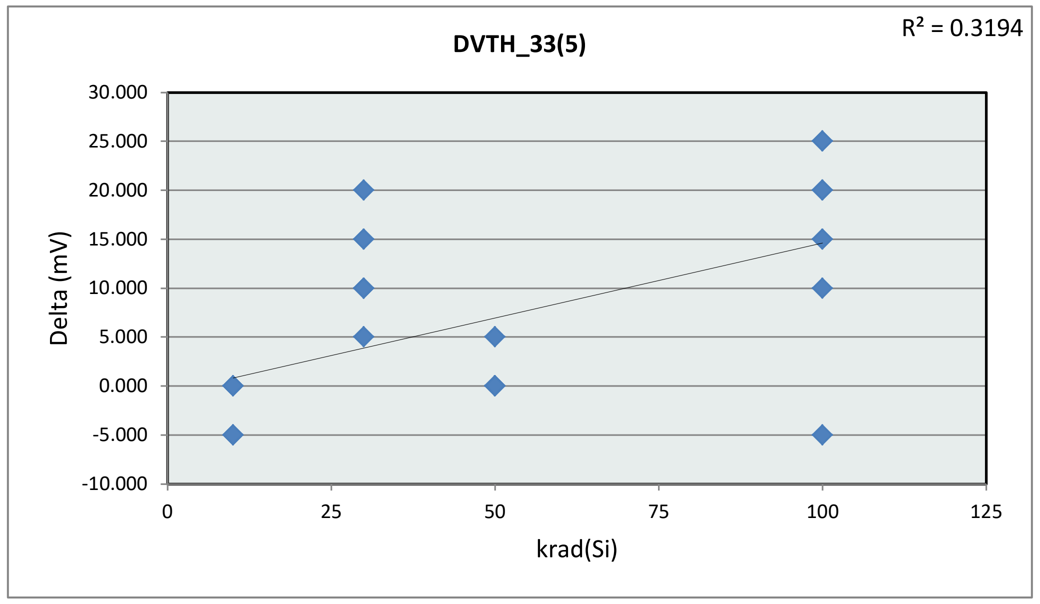
	VIDL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-15.000	-25.000	-10.000
Average	-17.500	-7.500	-16.250	-8.750
Max	-5.000	-5.000	-5.000	-5.000
UL				



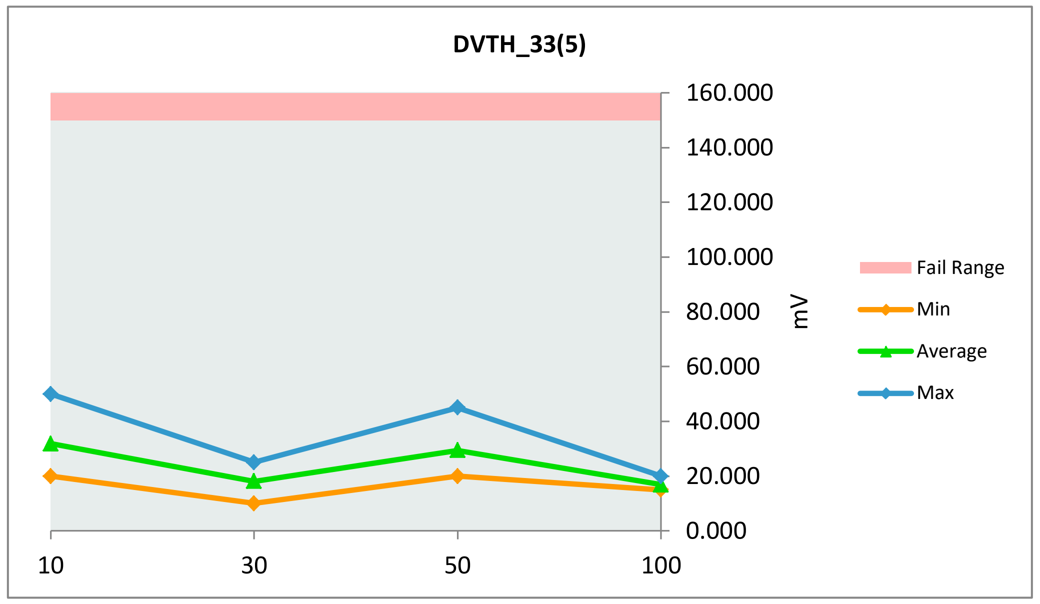
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	30.000	30.000	0.000
10	5	30.000	30.000	0.000
10	7	20.000	20.000	0.000
10	11	45.000	50.000	-5.000
10	15	20.000	20.000	0.000
10	20	35.000	40.000	-5.000
10	21	20.000	20.000	0.000
10	24	40.000	45.000	-5.000
30	1	30.000	20.000	10.000
30	5	30.000	15.000	15.000
30	7	20.000	10.000	10.000
30	11	45.000	25.000	20.000
30	15	20.000	10.000	10.000
30	20	35.000	25.000	10.000
30	21	20.000	15.000	5.000
30	24	40.000	25.000	15.000
50	1	30.000	30.000	0.000
50	5	30.000	25.000	5.000
50	7	20.000	20.000	0.000
50	11	45.000	45.000	0.000
50	15	20.000	20.000	0.000
50	20	35.000	35.000	0.000
50	21	20.000	20.000	0.000
50	24	40.000	40.000	0.000
100	3	35.000	15.000	20.000
100	8	35.000	15.000	20.000
100	12	30.000	15.000	15.000
100	13	45.000	20.000	25.000
100	16	30.000	15.000	15.000
100	17	15.000	20.000	-5.000
100	18	25.000	15.000	10.000
100	19	45.000	20.000	25.000
	Max	45.000	50.000	25.000
	Average	30.625	24.063	6.563
	Min	15.000	10.000	-5.000
	Std Dev	9.311	10.506	9.197

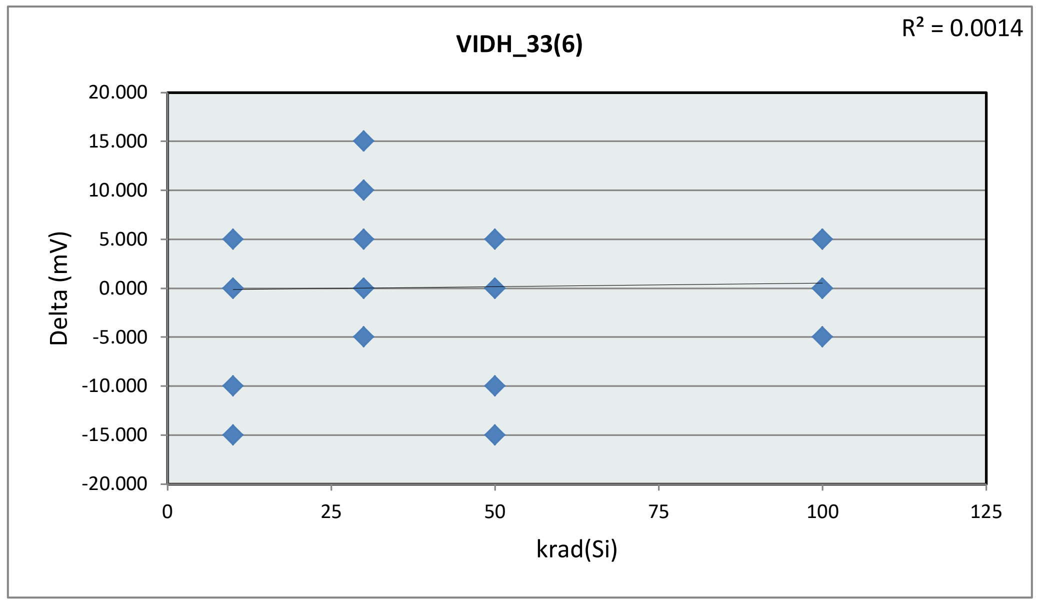


	DVTH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	20.000	15.000
Average	31.875	18.125	29.375	16.875
Max	50.000	25.000	45.000	20.000
UL	150.000	150.000	150.000	150.000

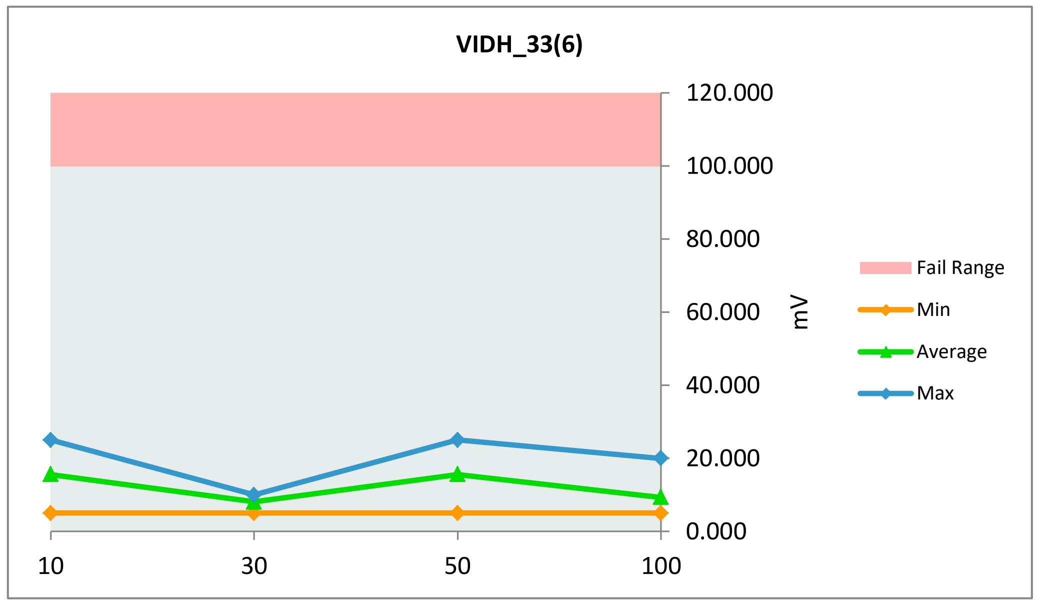


LDR Biased TID Report
SN55LVCP22A-SP

		VIDH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	25.000	25.000	0.000
10	5	5.000	5.000	0.000
10	7	15.000	15.000	0.000
10	11	25.000	20.000	5.000
10	15	5.000	5.000	0.000
10	20	5.000	20.000	-15.000
10	21	20.000	20.000	0.000
10	24	5.000	15.000	-10.000
30	1	25.000	10.000	15.000
30	5	5.000	5.000	0.000
30	7	15.000	10.000	5.000
30	11	25.000	10.000	15.000
30	15	5.000	5.000	0.000
30	20	5.000	10.000	-5.000
30	21	20.000	10.000	10.000
30	24	5.000	5.000	0.000
50	1	25.000	20.000	5.000
50	5	5.000	5.000	0.000
50	7	15.000	15.000	0.000
50	11	25.000	25.000	0.000
50	15	5.000	5.000	0.000
50	20	5.000	20.000	-15.000
50	21	20.000	20.000	0.000
50	24	5.000	15.000	-10.000
100	3	5.000	5.000	0.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	25.000	20.000	5.000
100	16	5.000	5.000	0.000
100	17	15.000	10.000	5.000
100	18	15.000	15.000	0.000
100	19	5.000	10.000	-5.000
	Max	25.000	25.000	15.000
	Average	12.344	12.188	0.156
	Min	5.000	5.000	-15.000
	Std Dev	8.518	6.713	6.658



	VIDH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	15.625	8.125	15.625	9.375
Max	25.000	10.000	25.000	20.000
UL	100.000	100.000	100.000	100.000



LDR Biased TID Report
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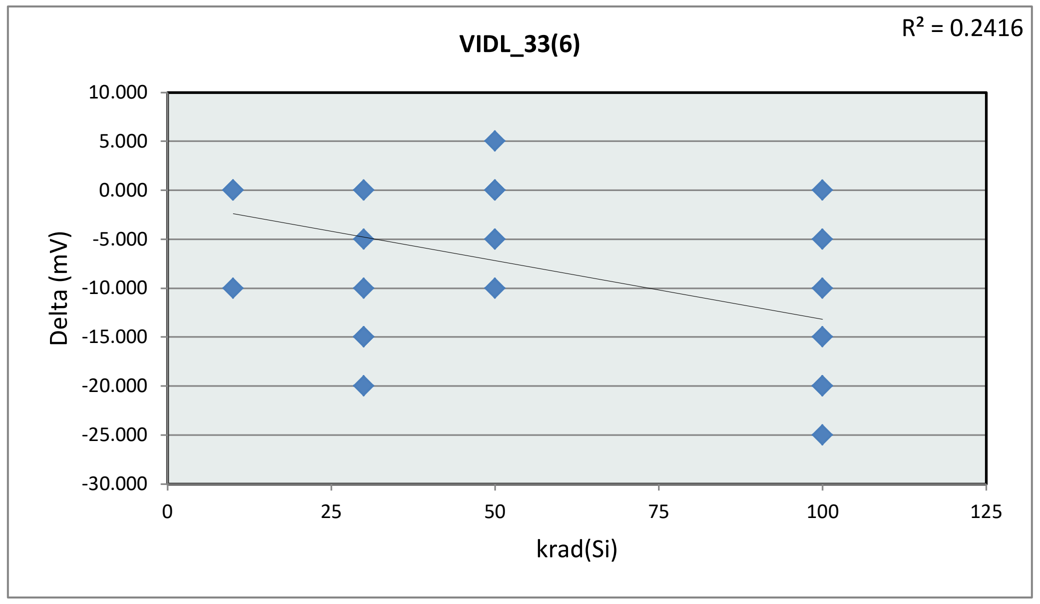
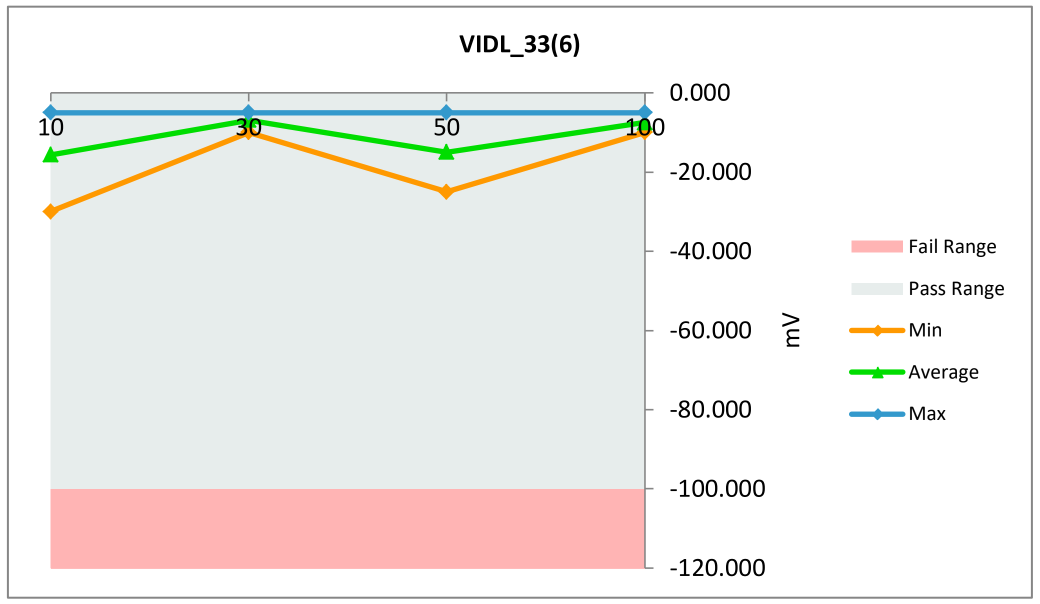
	VIDL_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-10.000	-10.000	0.000
10	5	-25.000	-25.000	0.000
10	7	-5.000	-5.000	0.000
10	11	-20.000	-20.000	0.000
10	15	-20.000	-10.000	-10.000
10	20	-20.000	-20.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-30.000	-30.000	0.000
30	1	-10.000	-5.000	-5.000
30	5	-25.000	-10.000	-15.000
30	7	-5.000	-5.000	0.000
30	11	-20.000	-10.000	-10.000
30	15	-20.000	-5.000	-15.000
30	20	-20.000	-5.000	-15.000
30	21	-5.000	-5.000	0.000
30	24	-30.000	-10.000	-20.000
50	1	-10.000	-10.000	0.000
50	5	-25.000	-25.000	0.000
50	7	-5.000	-5.000	0.000
50	11	-20.000	-25.000	5.000
50	15	-20.000	-10.000	-10.000
50	20	-20.000	-15.000	-5.000
50	21	-5.000	-5.000	0.000
50	24	-30.000	-25.000	-5.000
100	3	-25.000	-10.000	-15.000
100	8	-35.000	-10.000	-25.000
100	12	-25.000	-5.000	-20.000
100	13	-25.000	-5.000	-20.000
100	16	-20.000	-10.000	-10.000
100	17	-5.000	-5.000	0.000
100	18	-10.000	-5.000	-5.000
100	19	-30.000	-10.000	-20.000
	Max	-5.000	-5.000	5.000
	Average	-18.125	-11.250	-6.875
	Min	-35.000	-30.000	-25.000
	Std Dev	9.224	7.620	8.304



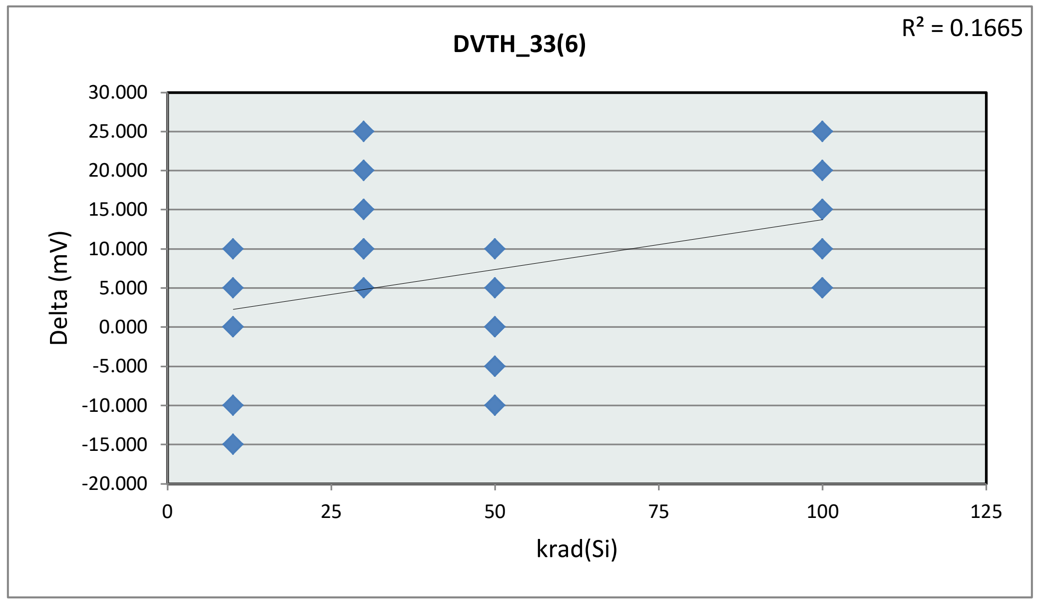
	VIDL_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-30.000	-10.000	-25.000	-10.000
Average	-15.625	-6.875	-15.000	-7.500
Max	-5.000	-5.000	-5.000	-5.000
UL				



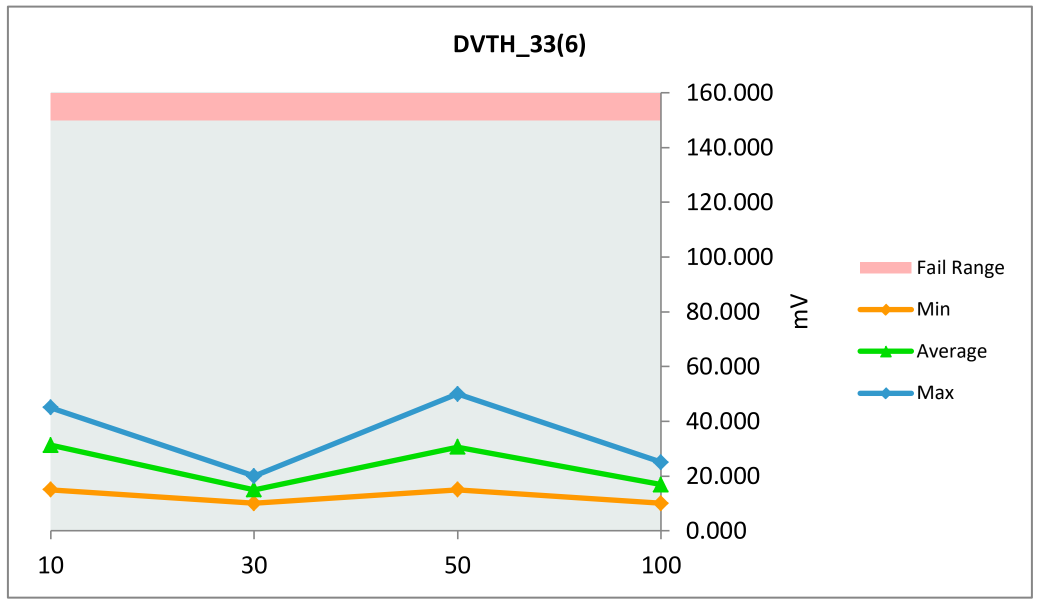
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	35.000	35.000	0.000
10	5	30.000	30.000	0.000
10	7	20.000	20.000	0.000
10	11	45.000	40.000	5.000
10	15	25.000	15.000	10.000
10	20	25.000	40.000	-15.000
10	21	25.000	25.000	0.000
10	24	35.000	45.000	-10.000
30	1	35.000	15.000	20.000
30	5	30.000	15.000	15.000
30	7	20.000	15.000	5.000
30	11	45.000	20.000	25.000
30	15	25.000	10.000	15.000
30	20	25.000	15.000	10.000
30	21	25.000	15.000	10.000
30	24	35.000	15.000	20.000
50	1	35.000	30.000	5.000
50	5	30.000	30.000	0.000
50	7	20.000	20.000	0.000
50	11	45.000	50.000	-5.000
50	15	25.000	15.000	10.000
50	20	25.000	35.000	-10.000
50	21	25.000	25.000	0.000
50	24	35.000	40.000	-5.000
100	3	30.000	15.000	15.000
100	8	40.000	15.000	25.000
100	12	30.000	10.000	20.000
100	13	50.000	25.000	25.000
100	16	25.000	15.000	10.000
100	17	20.000	15.000	5.000
100	18	25.000	20.000	5.000
100	19	35.000	20.000	15.000
	Max	50.000	50.000	25.000
	Average	30.469	23.438	7.031
	Min	20.000	10.000	-15.000
	Std Dev	8.068	10.883	10.615

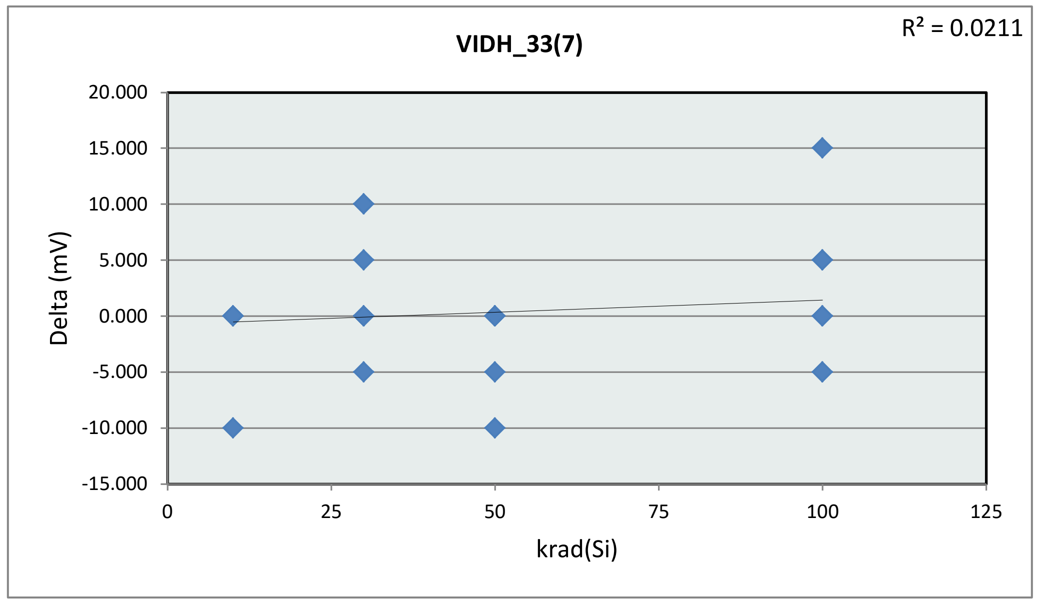


	DVTH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	15.000	10.000
Average	31.250	15.000	30.625	16.875
Max	45.000	20.000	50.000	25.000
UL	150.000	150.000	150.000	150.000

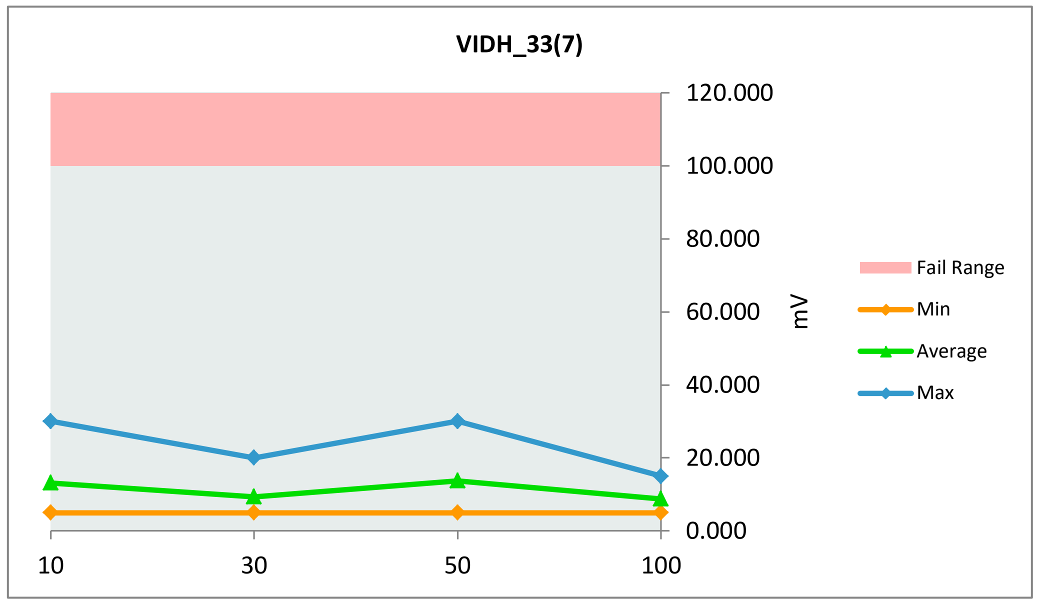


LDR Biased TID Report
SN55LVCP22A-SP

		VIDH_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.000	5.000	0.000
10	5	5.000	5.000	0.000
10	7	5.000	5.000	0.000
10	11	25.000	25.000	0.000
10	15	5.000	5.000	0.000
10	20	30.000	30.000	0.000
10	21	5.000	15.000	-10.000
10	24	15.000	15.000	0.000
30	1	5.000	5.000	0.000
30	5	5.000	5.000	0.000
30	7	5.000	5.000	0.000
30	11	25.000	15.000	10.000
30	15	5.000	5.000	0.000
30	20	30.000	20.000	10.000
30	21	5.000	10.000	-5.000
30	24	15.000	10.000	5.000
50	1	5.000	5.000	0.000
50	5	5.000	5.000	0.000
50	7	5.000	5.000	0.000
50	11	25.000	25.000	0.000
50	15	5.000	5.000	0.000
50	20	30.000	30.000	0.000
50	21	5.000	15.000	-10.000
50	24	15.000	20.000	-5.000
100	3	15.000	10.000	5.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	5.000	10.000	-5.000
100	16	5.000	5.000	0.000
100	17	10.000	15.000	-5.000
100	18	20.000	5.000	15.000
100	19	20.000	15.000	5.000
	Max	30.000	30.000	15.000
	Average	11.563	11.250	0.313
	Min	5.000	5.000	-10.000
	Std Dev	9.108	7.931	5.070

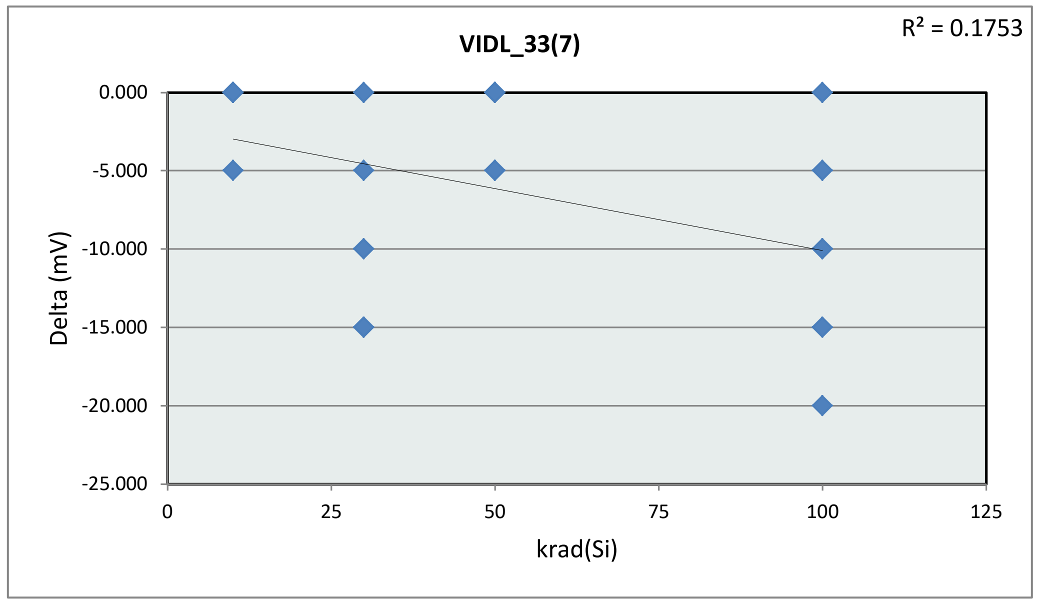


	VIDH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	13.125	9.375	13.750	8.750
Max	30.000	20.000	30.000	15.000
UL	100.000	100.000	100.000	100.000

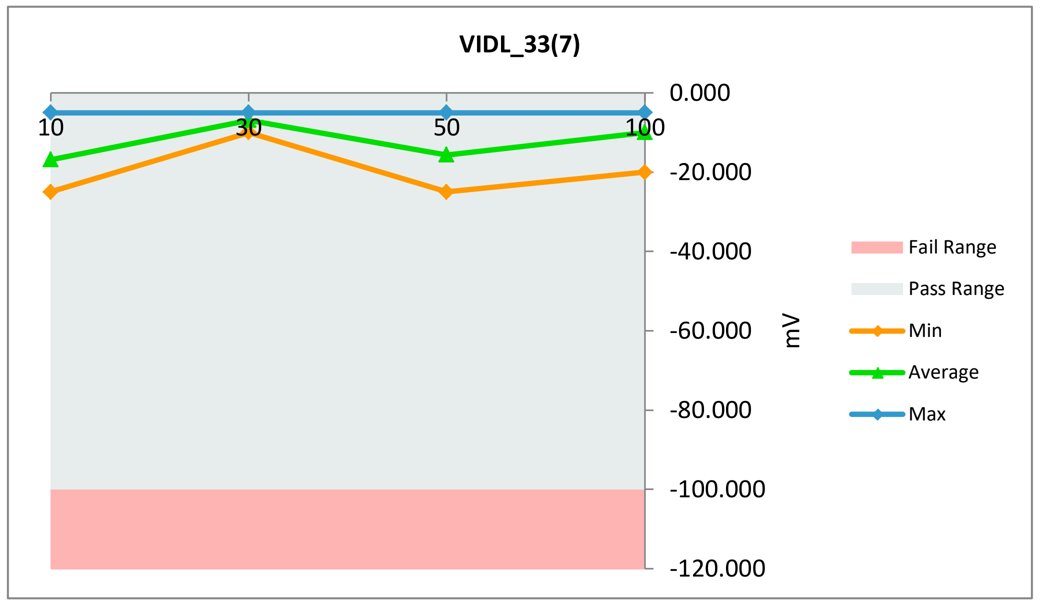


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-25.000	-25.000	0.000
10	5	-25.000	-25.000	0.000
10	7	-15.000	-15.000	0.000
10	11	-20.000	-20.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-5.000	-5.000	0.000
10	21	-10.000	-5.000	-5.000
10	24	-25.000	-25.000	0.000
30	1	-25.000	-10.000	-15.000
30	5	-25.000	-10.000	-15.000
30	7	-15.000	-5.000	-10.000
30	11	-20.000	-5.000	-15.000
30	15	-15.000	-5.000	-10.000
30	20	-5.000	-5.000	0.000
30	21	-10.000	-5.000	-5.000
30	24	-25.000	-10.000	-15.000
50	1	-25.000	-25.000	0.000
50	5	-25.000	-20.000	-5.000
50	7	-15.000	-15.000	0.000
50	11	-20.000	-15.000	-5.000
50	15	-15.000	-15.000	0.000
50	20	-5.000	-5.000	0.000
50	21	-10.000	-5.000	-5.000
50	24	-25.000	-25.000	0.000
100	3	-15.000	-5.000	-10.000
100	8	-30.000	-20.000	-10.000
100	12	-25.000	-10.000	-15.000
100	13	-30.000	-10.000	-20.000
100	16	-20.000	-10.000	-10.000
100	17	-5.000	-5.000	0.000
100	18	-15.000	-10.000	-5.000
100	19	-25.000	-10.000	-15.000
	Max	-5.000	-5.000	0.000
	Average	-18.281	-12.344	-5.938
	Min	-30.000	-25.000	-20.000
	Std Dev	7.579	7.294	6.405



	VIDL_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-10.000	-25.000	-20.000
Average	-16.875	-6.875	-15.625	-10.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



LDR Biased TID Report
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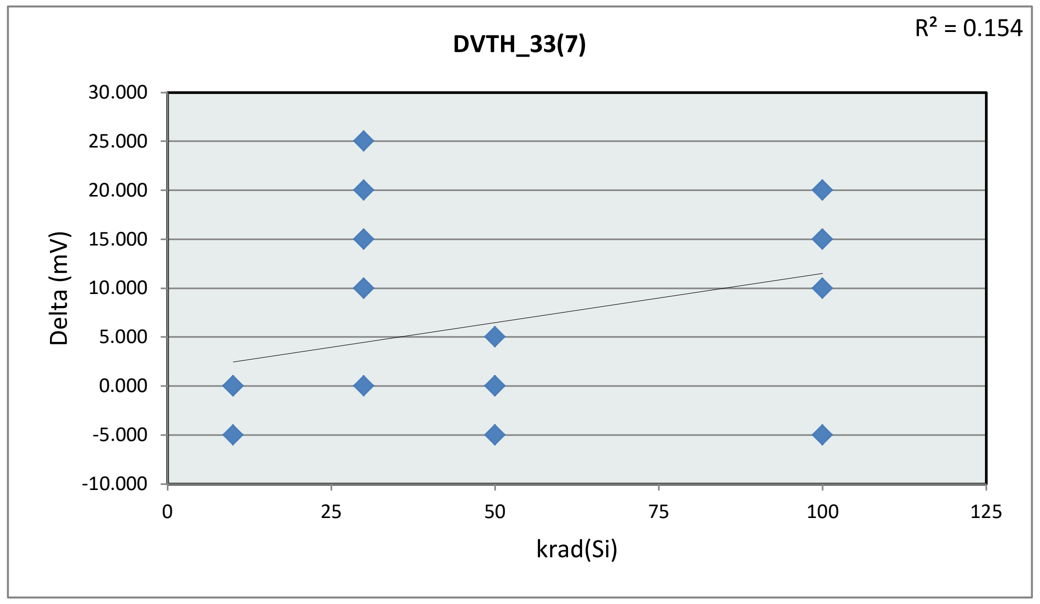
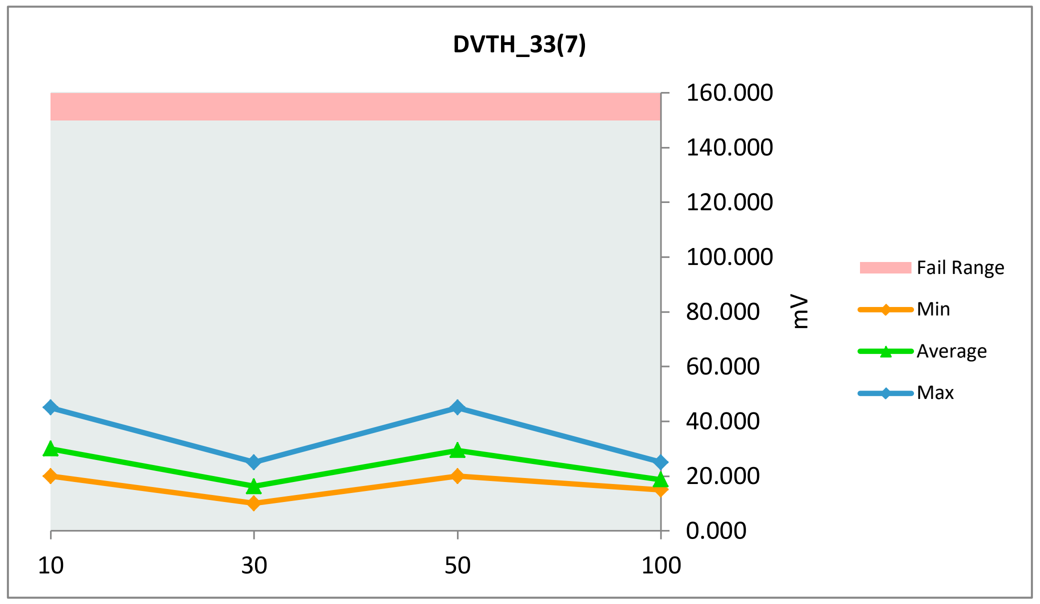
	DVTH_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	30.000	30.000	0.000
10	5	30.000	30.000	0.000
10	7	20.000	20.000	0.000
10	11	45.000	45.000	0.000
10	15	20.000	20.000	0.000
10	20	35.000	35.000	0.000
10	21	15.000	20.000	-5.000
10	24	40.000	40.000	0.000
30	1	30.000	15.000	15.000
30	5	30.000	15.000	15.000
30	7	20.000	10.000	10.000
30	11	45.000	20.000	25.000
30	15	20.000	10.000	10.000
30	20	35.000	25.000	10.000
30	21	15.000	15.000	0.000
30	24	40.000	20.000	20.000
50	1	30.000	30.000	0.000
50	5	30.000	25.000	5.000
50	7	20.000	20.000	0.000
50	11	45.000	40.000	5.000
50	15	20.000	20.000	0.000
50	20	35.000	35.000	0.000
50	21	15.000	20.000	-5.000
50	24	40.000	45.000	-5.000
100	3	30.000	15.000	15.000
100	8	35.000	25.000	10.000
100	12	30.000	15.000	15.000
100	13	35.000	20.000	15.000
100	16	25.000	15.000	10.000
100	17	15.000	20.000	-5.000
100	18	35.000	15.000	20.000
100	19	45.000	25.000	20.000
	Max	45.000	45.000	25.000
	Average	29.844	23.594	6.250
	Min	15.000	10.000	-5.000
	Std Dev	9.629	9.608	8.707



	DVTH_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	mV
Min Limit		mV

krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	20.000	15.000
Average	30.000	16.250	29.375	18.750
Max	45.000	25.000	45.000	25.000
UL	150.000	150.000	150.000	150.000



LDR Biased TID Report
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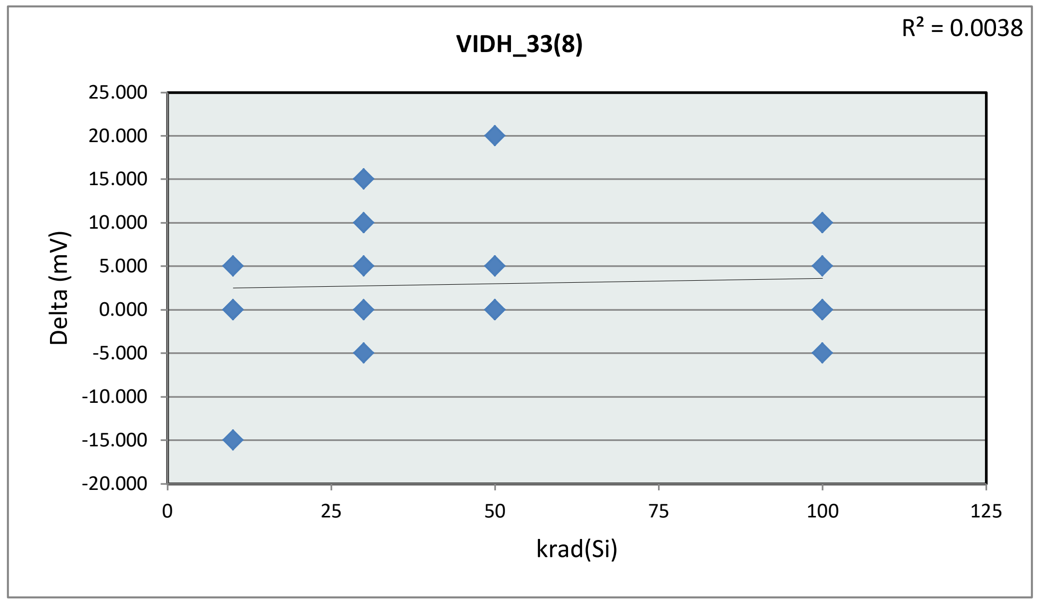
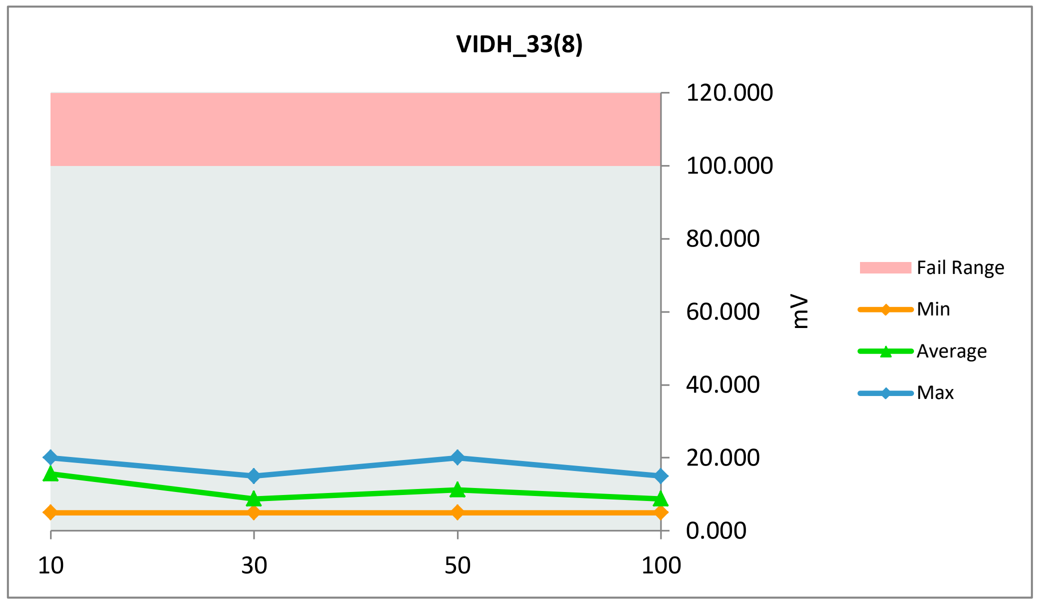
	VIDH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	25.000	20.000	5.000
10	5	5.000	5.000	0.000
10	7	15.000	15.000	0.000
10	11	5.000	20.000	-15.000
10	15	5.000	5.000	0.000
10	20	25.000	20.000	5.000
10	21	20.000	20.000	0.000
10	24	20.000	20.000	0.000
30	1	25.000	15.000	10.000
30	5	5.000	5.000	0.000
30	7	15.000	10.000	5.000
30	11	5.000	10.000	-5.000
30	15	5.000	5.000	0.000
30	20	25.000	10.000	15.000
30	21	20.000	10.000	10.000
30	24	20.000	5.000	15.000
50	1	25.000	20.000	5.000
50	5	5.000	5.000	0.000
50	7	15.000	15.000	0.000
50	11	5.000	5.000	0.000
50	15	5.000	5.000	0.000
50	20	25.000	5.000	20.000
50	21	20.000	20.000	0.000
50	24	20.000	15.000	5.000
100	3	5.000	5.000	0.000
100	8	5.000	5.000	0.000
100	12	10.000	10.000	0.000
100	13	25.000	15.000	10.000
100	16	5.000	5.000	0.000
100	17	15.000	10.000	5.000
100	18	20.000	10.000	10.000
100	19	5.000	10.000	-5.000
	Max	25.000	20.000	20.000
	Average	14.063	11.094	2.969
	Min	5.000	5.000	-15.000
	Std Dev	8.370	5.921	6.703



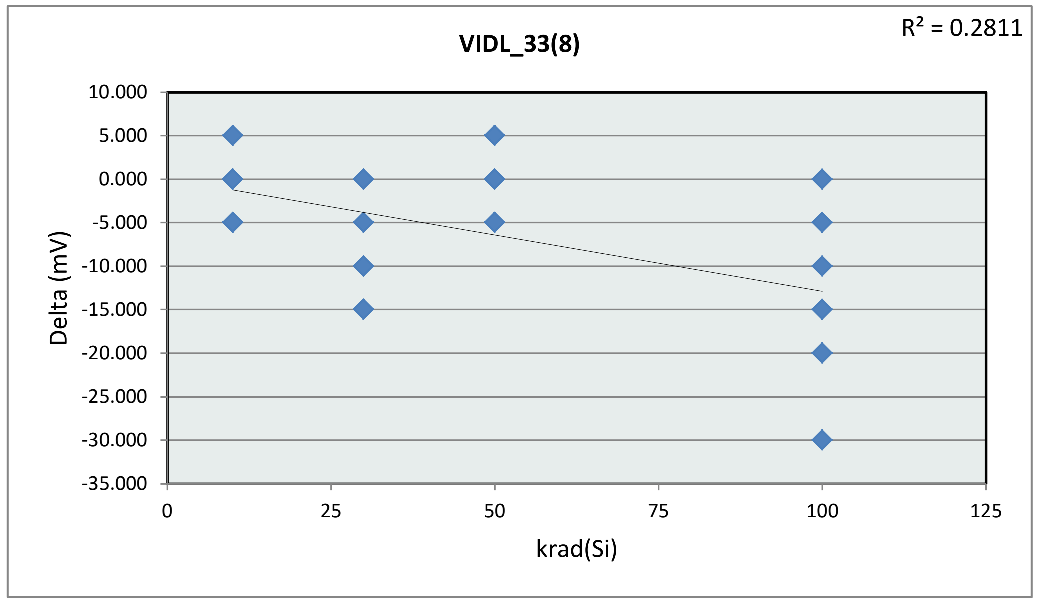
	VIDH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	15.625	8.750	11.250	8.750
Max	20.000	15.000	20.000	15.000
UL	100.000	100.000	100.000	100.000



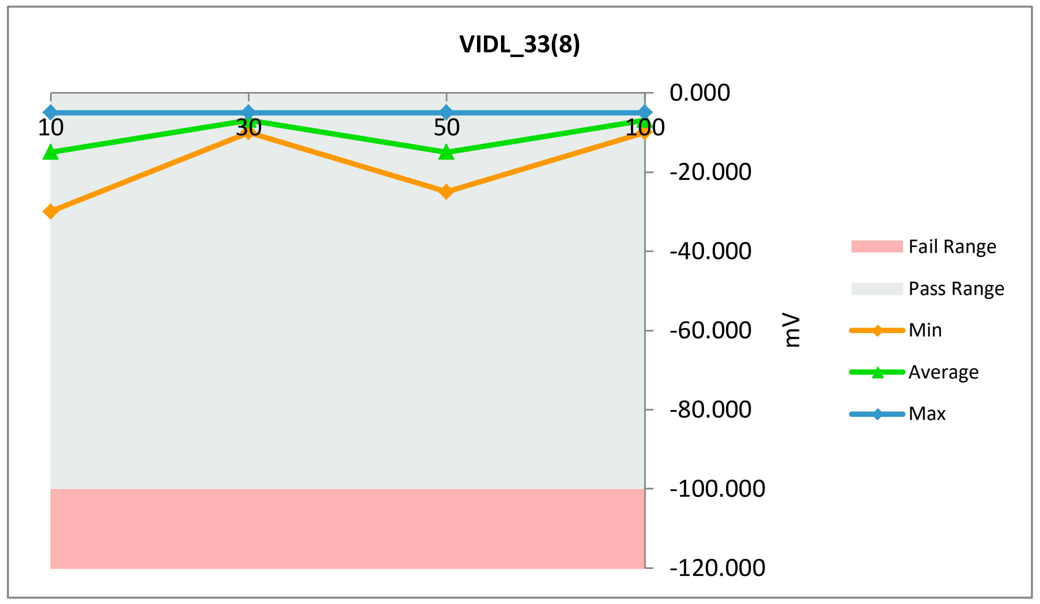
LDR Biased TID Report
SN55LVCP22A-SP

	VIDL_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-10.000	-10.000	0.000
10	5	-25.000	-20.000	-5.000
10	7	-5.000	-5.000	0.000
10	11	-25.000	-20.000	-5.000
10	15	-15.000	-15.000	0.000
10	20	-15.000	-15.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-25.000	-30.000	5.000
30	1	-10.000	-5.000	-5.000
30	5	-25.000	-10.000	-15.000
30	7	-5.000	-5.000	0.000
30	11	-25.000	-10.000	-15.000
30	15	-15.000	-5.000	-10.000
30	20	-15.000	-5.000	-10.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-10.000	-15.000
50	1	-10.000	-10.000	0.000
50	5	-25.000	-25.000	0.000
50	7	-5.000	-5.000	0.000
50	11	-25.000	-20.000	-5.000
50	15	-15.000	-10.000	-5.000
50	20	-15.000	-20.000	5.000
50	21	-5.000	-5.000	0.000
50	24	-25.000	-25.000	0.000
100	3	-30.000	-10.000	-20.000
100	8	-35.000	-5.000	-30.000
100	12	-25.000	-10.000	-15.000
100	13	-20.000	-5.000	-15.000
100	16	-15.000	-5.000	-10.000
100	17	-5.000	-5.000	0.000
100	18	-10.000	-5.000	-5.000
100	19	-30.000	-10.000	-20.000
	Max	-5.000	-5.000	5.000
	Average	-17.031	-10.938	-6.094
	Min	-35.000	-30.000	-30.000
	Std Dev	9.057	7.233	8.302



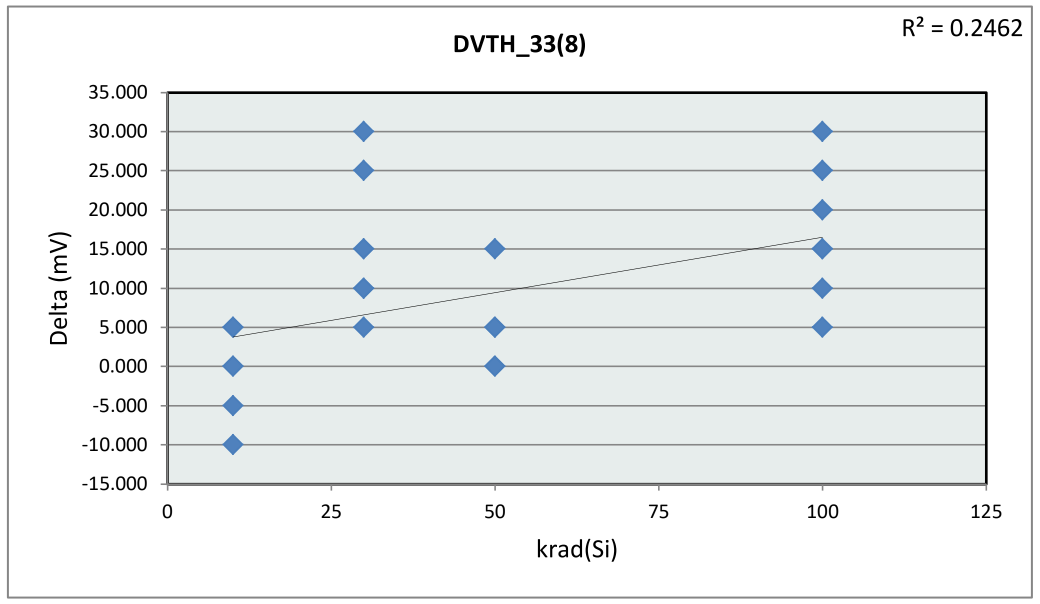
	VIDL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-30.000	-10.000	-25.000	-10.000
Average	-15.000	-6.875	-15.000	-6.875
Max	-5.000	-5.000	-5.000	-5.000
UL				



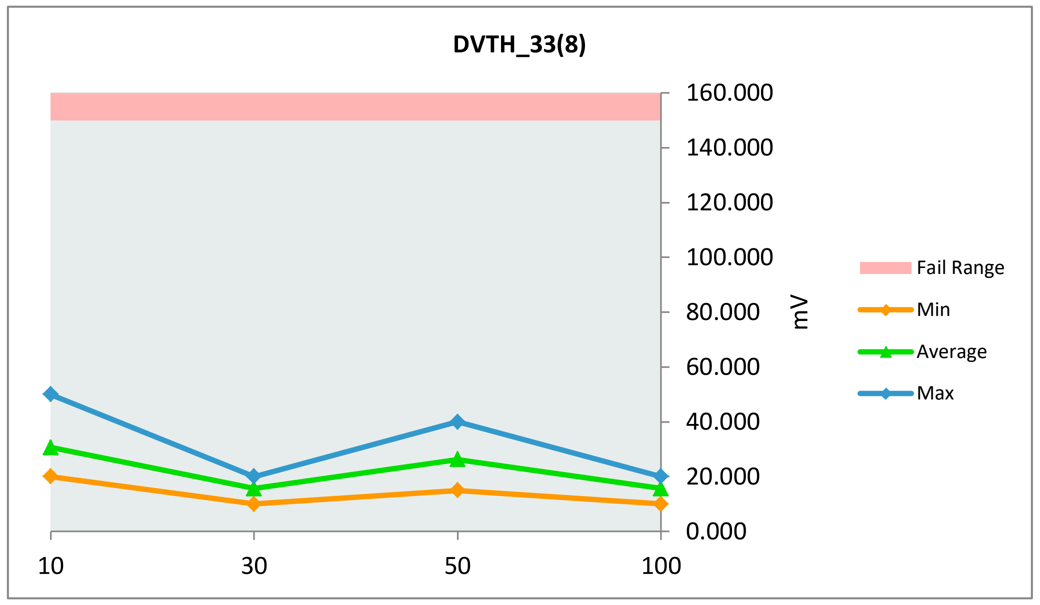
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	35.000	30.000	5.000
10	5	30.000	25.000	5.000
10	7	20.000	20.000	0.000
10	11	30.000	40.000	-10.000
10	15	20.000	20.000	0.000
10	20	40.000	35.000	5.000
10	21	25.000	25.000	0.000
10	24	45.000	50.000	-5.000
30	1	35.000	20.000	15.000
30	5	30.000	15.000	15.000
30	7	20.000	15.000	5.000
30	11	30.000	20.000	10.000
30	15	20.000	10.000	10.000
30	20	40.000	15.000	25.000
30	21	25.000	15.000	10.000
30	24	45.000	15.000	30.000
50	1	35.000	30.000	5.000
50	5	30.000	30.000	0.000
50	7	20.000	20.000	0.000
50	11	30.000	25.000	5.000
50	15	20.000	15.000	5.000
50	20	40.000	25.000	15.000
50	21	25.000	25.000	0.000
50	24	45.000	40.000	5.000
100	3	35.000	15.000	20.000
100	8	40.000	10.000	30.000
100	12	35.000	20.000	15.000
100	13	45.000	20.000	25.000
100	16	20.000	10.000	10.000
100	17	20.000	15.000	5.000
100	18	30.000	15.000	15.000
100	19	35.000	20.000	15.000
	Max	45.000	50.000	30.000
	Average	31.094	22.031	9.063
	Min	20.000	10.000	-10.000
	Std Dev	8.589	9.407	9.708



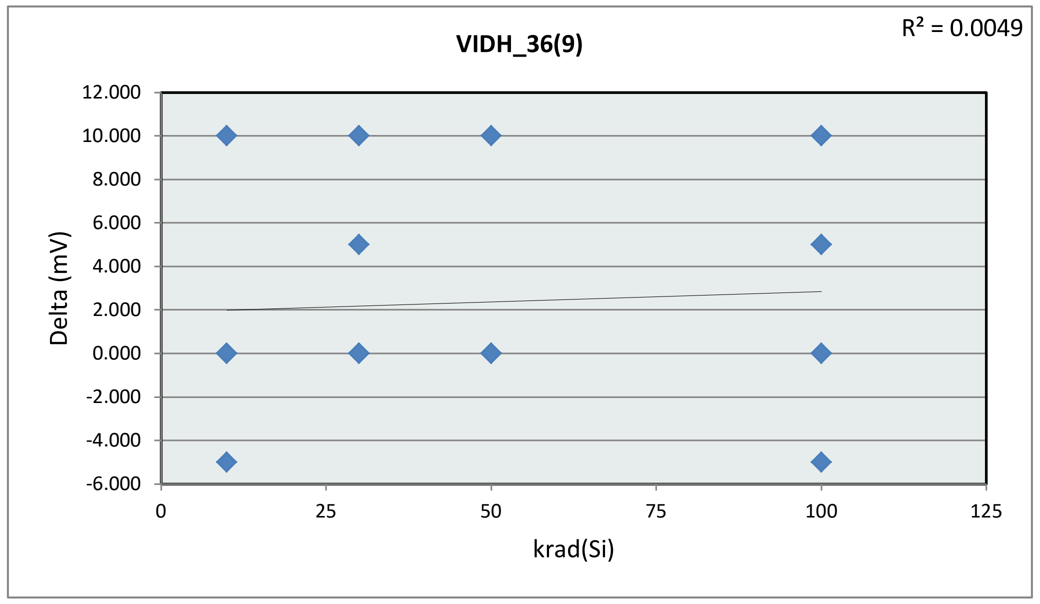
	DVTH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	15.000	10.000
Average	30.625	15.625	26.250	15.625
Max	50.000	20.000	40.000	20.000
UL	150.000	150.000	150.000	150.000



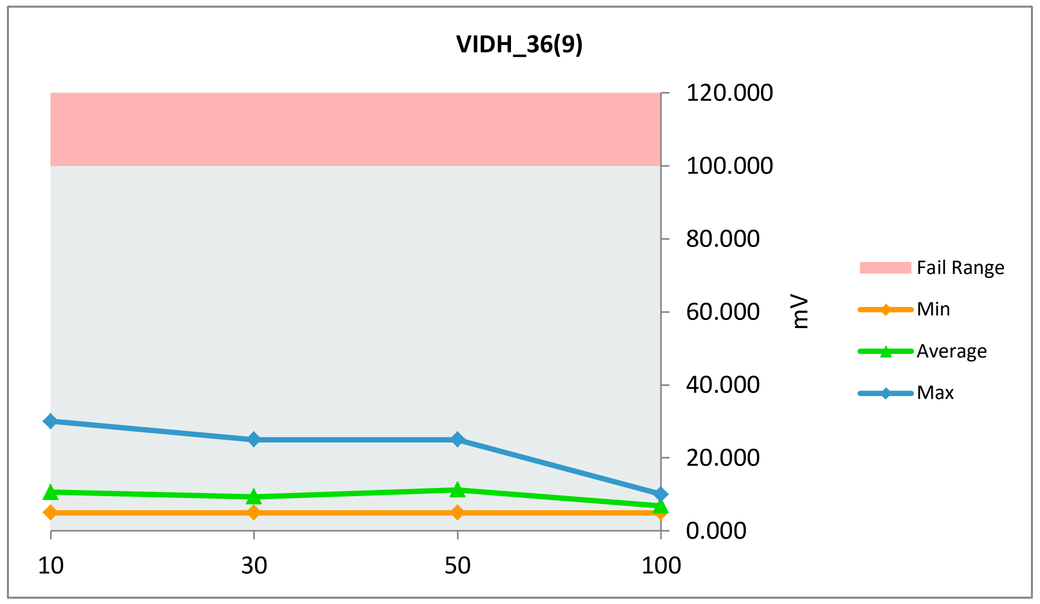
LDR Biased TID Report
SN55LVCP22A-SP

	VIDH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.000	5.000	0.000
10	5	5.000	5.000	0.000
10	7	5.000	5.000	0.000
10	11	25.000	25.000	0.000
10	15	5.000	5.000	0.000
10	20	25.000	30.000	-5.000
10	21	15.000	5.000	10.000
10	24	15.000	5.000	10.000
30	1	5.000	5.000	0.000
30	5	5.000	5.000	0.000
30	7	5.000	5.000	0.000
30	11	25.000	15.000	10.000
30	15	5.000	5.000	0.000
30	20	25.000	25.000	0.000
30	21	15.000	10.000	5.000
30	24	15.000	5.000	10.000
50	1	5.000	5.000	0.000
50	5	5.000	5.000	0.000
50	7	5.000	5.000	0.000
50	11	25.000	25.000	0.000
50	15	5.000	5.000	0.000
50	20	25.000	25.000	0.000
50	21	15.000	15.000	0.000
50	24	15.000	5.000	10.000
100	3	15.000	10.000	5.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	10.000	5.000	5.000
100	16	5.000	5.000	0.000
100	17	5.000	10.000	-5.000
100	18	15.000	5.000	10.000
100	19	20.000	10.000	10.000
	Max	25.000	30.000	10.000
	Average	11.875	9.531	2.344
	Min	5.000	5.000	-5.000
	Std Dev	7.906	7.763	4.576

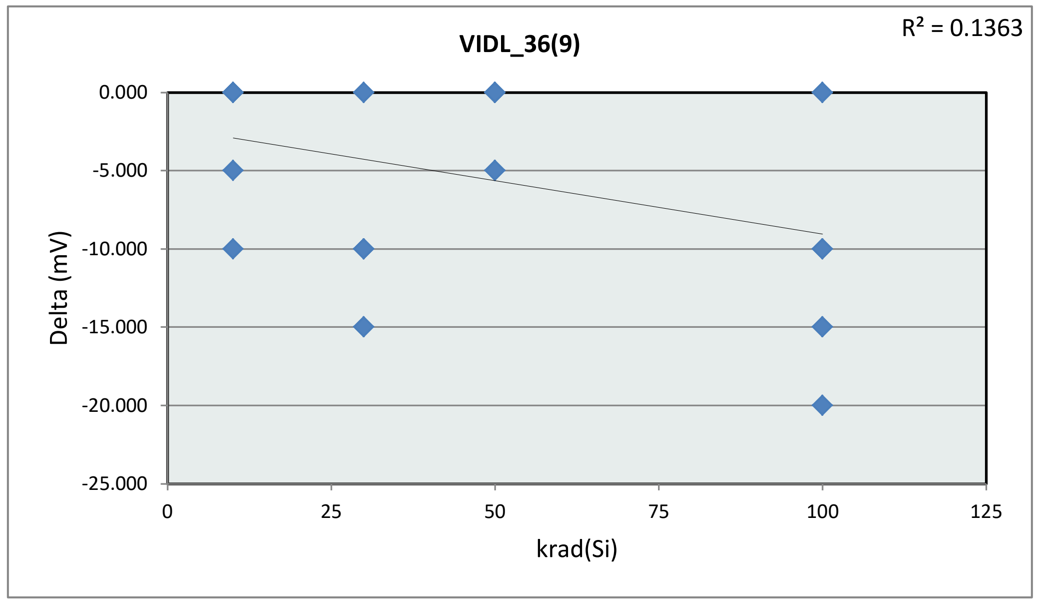


	VIDH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	10.625	9.375	11.250	6.875
Max	30.000	25.000	25.000	10.000
UL	100.000	100.000	100.000	100.000

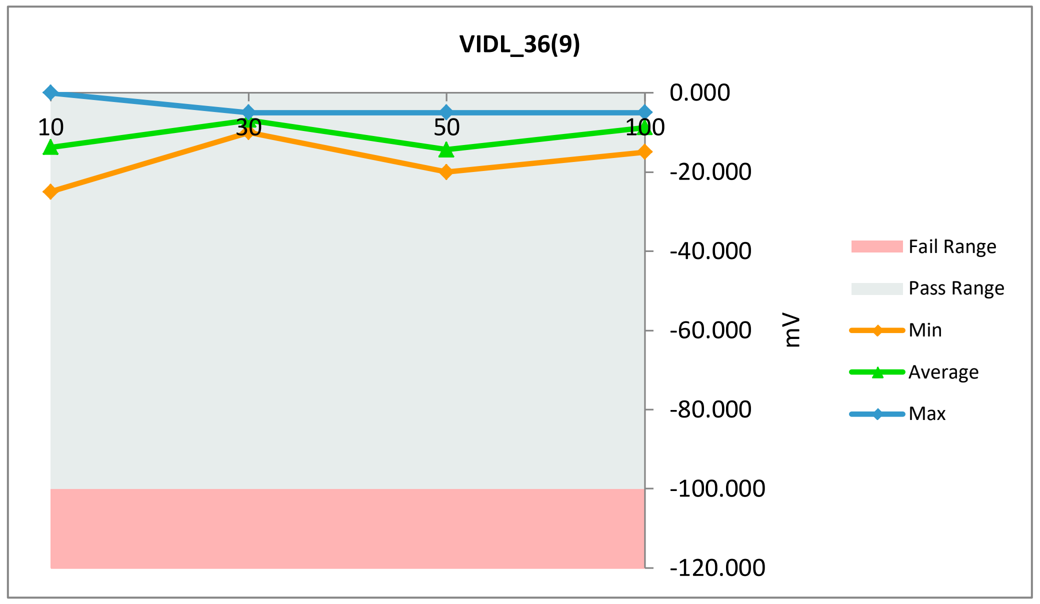


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-25.000	-25.000	0.000
10	5	-20.000	-20.000	0.000
10	7	-15.000	-5.000	-10.000
10	11	-15.000	-15.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-5.000	-5.000	0.000
10	21	-5.000	0.000	-5.000
10	24	-25.000	-25.000	0.000
30	1	-25.000	-10.000	-15.000
30	5	-20.000	-10.000	-10.000
30	7	-15.000	-5.000	-10.000
30	11	-15.000	-5.000	-10.000
30	15	-15.000	-5.000	-10.000
30	20	-5.000	-5.000	0.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-10.000	-15.000
50	1	-25.000	-20.000	-5.000
50	5	-20.000	-20.000	0.000
50	7	-15.000	-15.000	0.000
50	11	-15.000	-15.000	0.000
50	15	-15.000	-15.000	0.000
50	20	-5.000	-5.000	0.000
50	21	-5.000	-5.000	0.000
50	24	-25.000	-20.000	-5.000
100	3	-15.000	-5.000	-10.000
100	8	-30.000	-10.000	-20.000
100	12	-20.000	-10.000	-10.000
100	13	-30.000	-15.000	-15.000
100	16	-20.000	-10.000	-10.000
100	17	-5.000	-5.000	0.000
100	18	-5.000	-5.000	0.000
100	19	-25.000	-10.000	-15.000
	Max	-5.000	0.000	0.000
	Average	-16.406	-10.938	-5.469
	Min	-30.000	-25.000	-20.000
	Std Dev	8.056	6.652	6.268



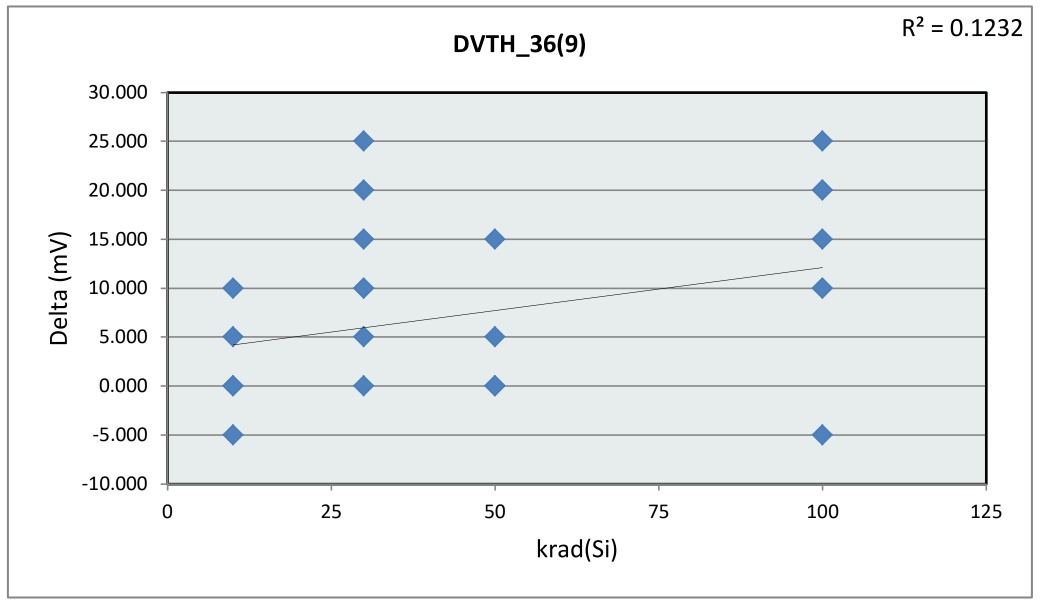
	VIDL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-10.000	-20.000	-15.000
Average	-13.750	-6.875	-14.375	-8.750
Max	0.000	-5.000	-5.000	-5.000
UL				



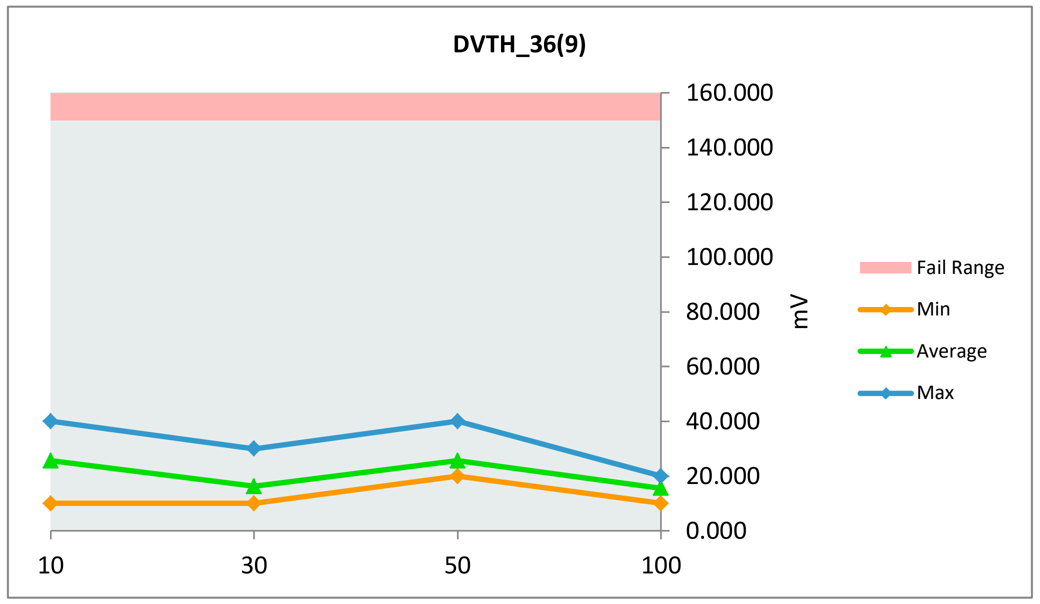
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	30.000	30.000	0.000
10	5	25.000	25.000	0.000
10	7	20.000	10.000	10.000
10	11	40.000	40.000	0.000
10	15	20.000	20.000	0.000
10	20	30.000	35.000	-5.000
10	21	20.000	15.000	5.000
10	24	40.000	30.000	10.000
30	1	30.000	15.000	15.000
30	5	25.000	15.000	10.000
30	7	20.000	10.000	10.000
30	11	40.000	20.000	20.000
30	15	20.000	10.000	10.000
30	20	30.000	30.000	0.000
30	21	20.000	15.000	5.000
30	24	40.000	15.000	25.000
50	1	30.000	25.000	5.000
50	5	25.000	25.000	0.000
50	7	20.000	20.000	0.000
50	11	40.000	40.000	0.000
50	15	20.000	20.000	0.000
50	20	30.000	30.000	0.000
50	21	20.000	20.000	0.000
50	24	40.000	25.000	15.000
100	3	30.000	15.000	15.000
100	8	35.000	15.000	20.000
100	12	25.000	15.000	10.000
100	13	40.000	20.000	20.000
100	16	25.000	15.000	10.000
100	17	10.000	15.000	-5.000
100	18	20.000	10.000	10.000
100	19	45.000	20.000	25.000
	Max	45.000	40.000	25.000
	Average	28.281	20.781	7.500
	Min	10.000	10.000	-5.000
	Std Dev	8.763	8.339	8.519

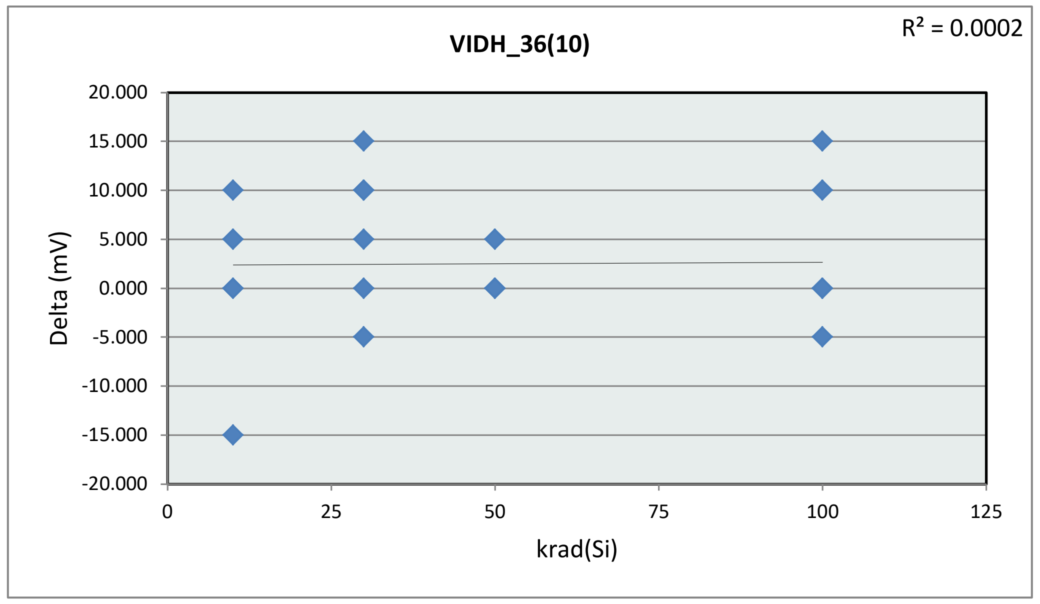


	DVTH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	10.000	20.000	10.000
Average	25.625	16.250	25.625	15.625
Max	40.000	30.000	40.000	20.000
UL	150.000	150.000	150.000	150.000

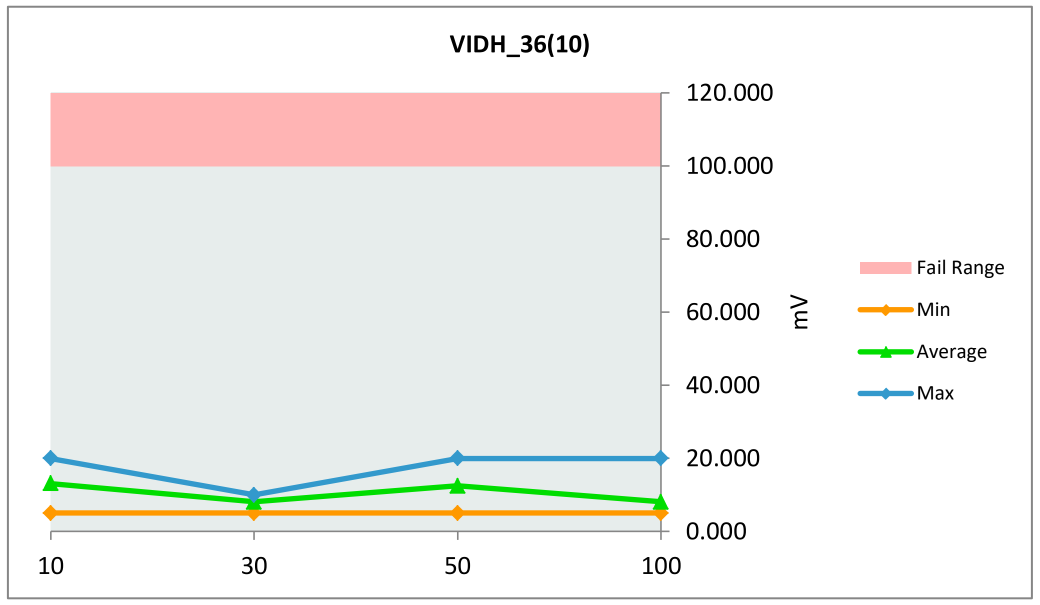


LDR Biased TID Report
SN55LVCP22A-SP

		VIDH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	20.000	20.000	0.000
10	5	5.000	5.000	0.000
10	7	15.000	15.000	0.000
10	11	5.000	20.000	-15.000
10	15	5.000	5.000	0.000
10	20	25.000	20.000	5.000
10	21	20.000	15.000	5.000
10	24	15.000	5.000	10.000
30	1	20.000	10.000	10.000
30	5	5.000	5.000	0.000
30	7	15.000	10.000	5.000
30	11	5.000	10.000	-5.000
30	15	5.000	5.000	0.000
30	20	25.000	10.000	15.000
30	21	20.000	10.000	10.000
30	24	15.000	5.000	10.000
50	1	20.000	20.000	0.000
50	5	5.000	5.000	0.000
50	7	15.000	15.000	0.000
50	11	5.000	5.000	0.000
50	15	5.000	5.000	0.000
50	20	25.000	20.000	5.000
50	21	20.000	15.000	5.000
50	24	15.000	15.000	0.000
100	3	5.000	5.000	0.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	25.000	10.000	15.000
100	16	5.000	5.000	0.000
100	17	15.000	20.000	-5.000
100	18	20.000	10.000	10.000
100	19	5.000	5.000	0.000
	Max	25.000	20.000	15.000
	Average	12.969	10.469	2.500
	Min	5.000	5.000	-15.000
	Std Dev	7.710	5.869	6.091

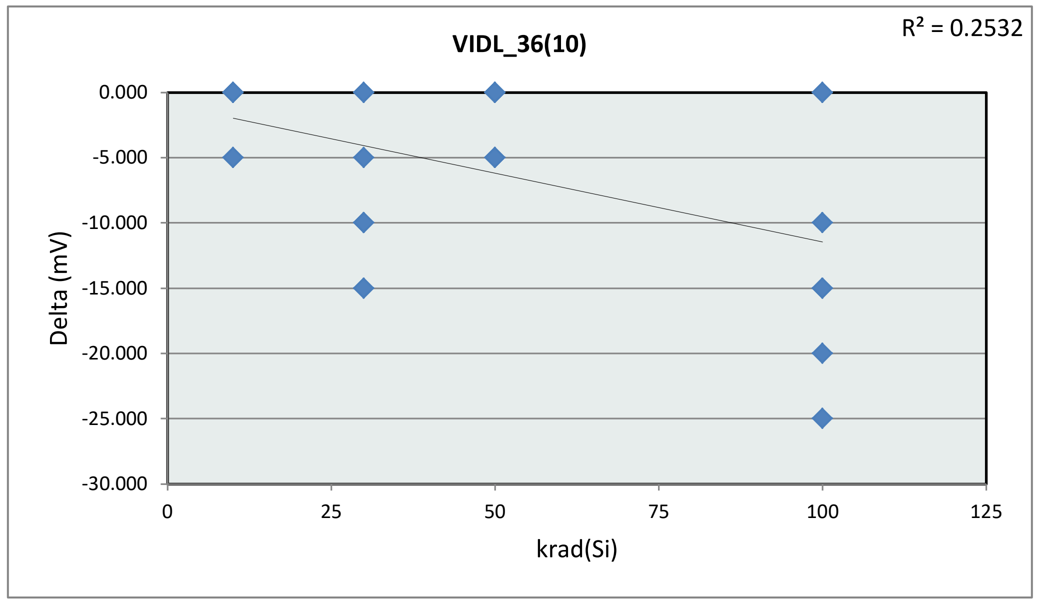


	VIDH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	13.125	8.125	12.500	8.125
Max	20.000	10.000	20.000	20.000
UL	100.000	100.000	100.000	100.000

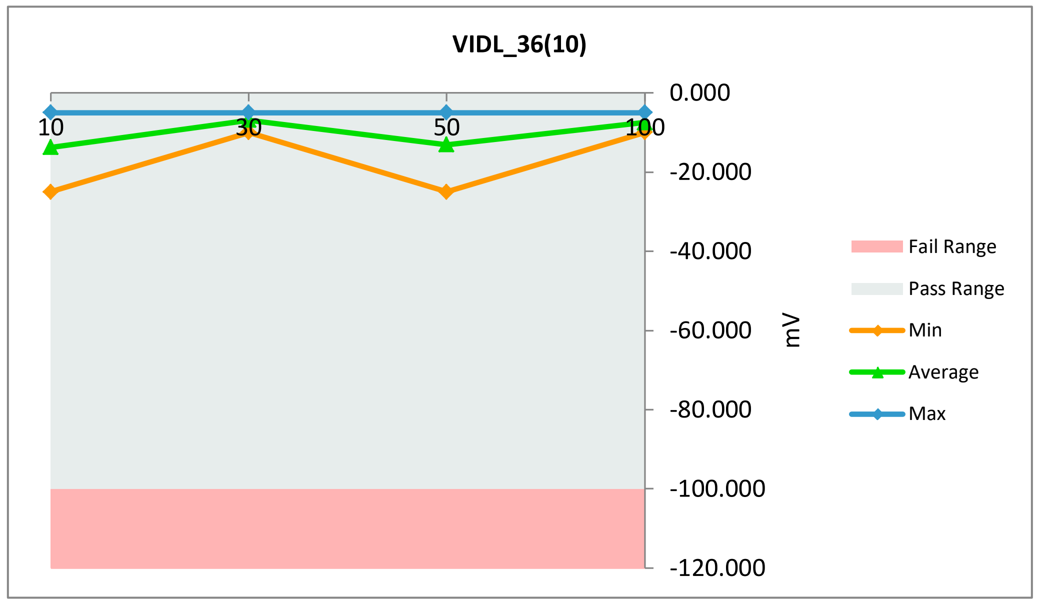


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_36(10)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-10.000	-10.000	0.000
10	5	-25.000	-20.000	-5.000
10	7	-5.000	-5.000	0.000
10	11	-20.000	-20.000	0.000
10	15	-15.000	-10.000	-5.000
10	20	-15.000	-15.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-25.000	-25.000	0.000
30	1	-10.000	-5.000	-5.000
30	5	-25.000	-10.000	-15.000
30	7	-5.000	-5.000	0.000
30	11	-20.000	-10.000	-10.000
30	15	-15.000	-5.000	-10.000
30	20	-15.000	-5.000	-10.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-10.000	-15.000
50	1	-10.000	-5.000	-5.000
50	5	-25.000	-20.000	-5.000
50	7	-5.000	-5.000	0.000
50	11	-20.000	-20.000	0.000
50	15	-15.000	-10.000	-5.000
50	20	-15.000	-15.000	0.000
50	21	-5.000	-5.000	0.000
50	24	-25.000	-25.000	0.000
100	3	-25.000	-10.000	-15.000
100	8	-35.000	-10.000	-25.000
100	12	-25.000	-10.000	-15.000
100	13	-20.000	-5.000	-15.000
100	16	-15.000	-5.000	-10.000
100	17	-5.000	-5.000	0.000
100	18	-5.000	-5.000	0.000
100	19	-30.000	-10.000	-20.000
	Max	-5.000	-5.000	0.000
	Average	-16.250	-10.313	-5.938
	Min	-35.000	-25.000	-25.000
	Std Dev	8.707	6.342	7.121



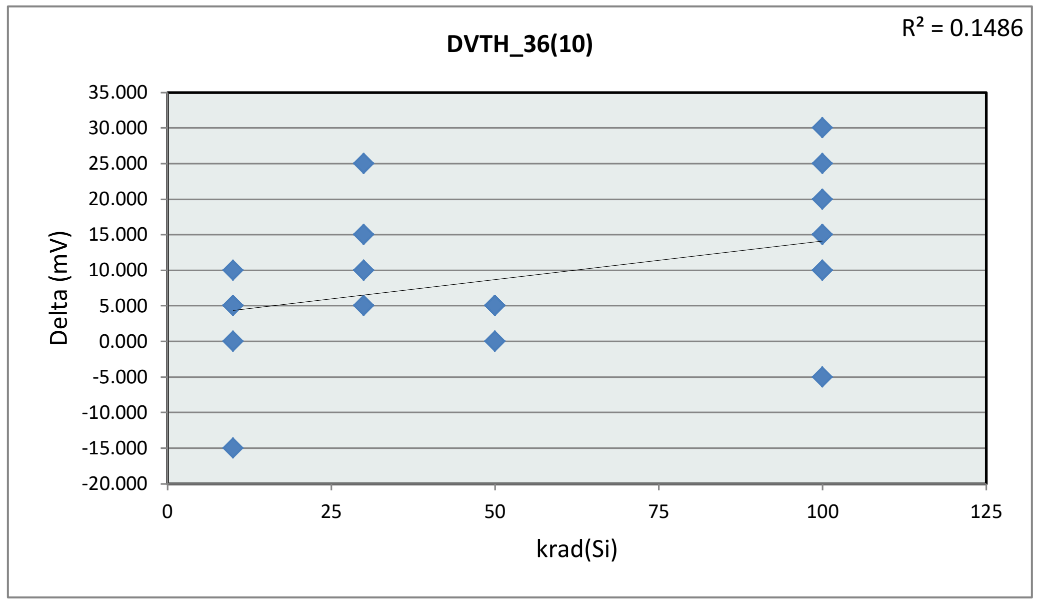
	VIDL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-10.000	-25.000	-10.000
Average	-13.750	-6.875	-13.125	-7.500
Max	-5.000	-5.000	-5.000	-5.000
UL				



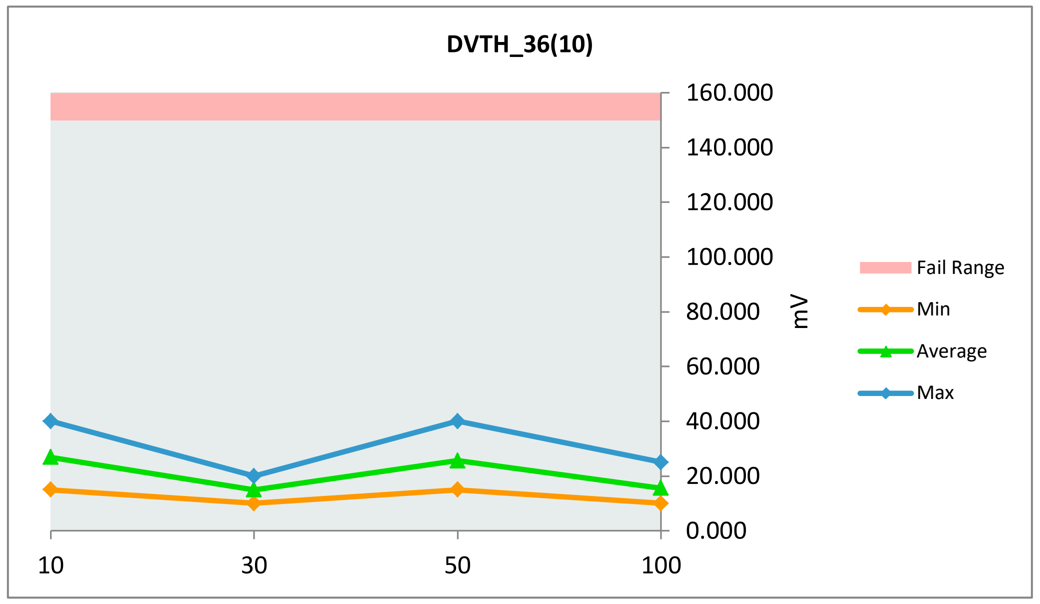
LDR Biased TID Report
SN55LVCP22A-SP

	DVTH_36(10)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	30.000	30.000	0.000
10	5	30.000	25.000	5.000
10	7	20.000	20.000	0.000
10	11	25.000	40.000	-15.000
10	15	20.000	15.000	5.000
10	20	40.000	35.000	5.000
10	21	25.000	20.000	5.000
10	24	40.000	30.000	10.000
30	1	30.000	15.000	15.000
30	5	30.000	15.000	15.000
30	7	20.000	15.000	5.000
30	11	25.000	20.000	5.000
30	15	20.000	10.000	10.000
30	20	40.000	15.000	25.000
30	21	25.000	15.000	10.000
30	24	40.000	15.000	25.000
50	1	30.000	25.000	5.000
50	5	30.000	25.000	5.000
50	7	20.000	20.000	0.000
50	11	25.000	25.000	0.000
50	15	20.000	15.000	5.000
50	20	40.000	35.000	5.000
50	21	25.000	20.000	5.000
50	24	40.000	40.000	0.000
100	3	30.000	15.000	15.000
100	8	40.000	15.000	25.000
100	12	30.000	15.000	15.000
100	13	45.000	15.000	30.000
100	16	20.000	10.000	10.000
100	17	20.000	25.000	-5.000
100	18	25.000	15.000	10.000
100	19	35.000	15.000	20.000
	Max	45.000	40.000	30.000
	Average	29.219	20.781	8.438
	Min	20.000	10.000	-15.000
	Std Dev	7.840	8.241	9.541

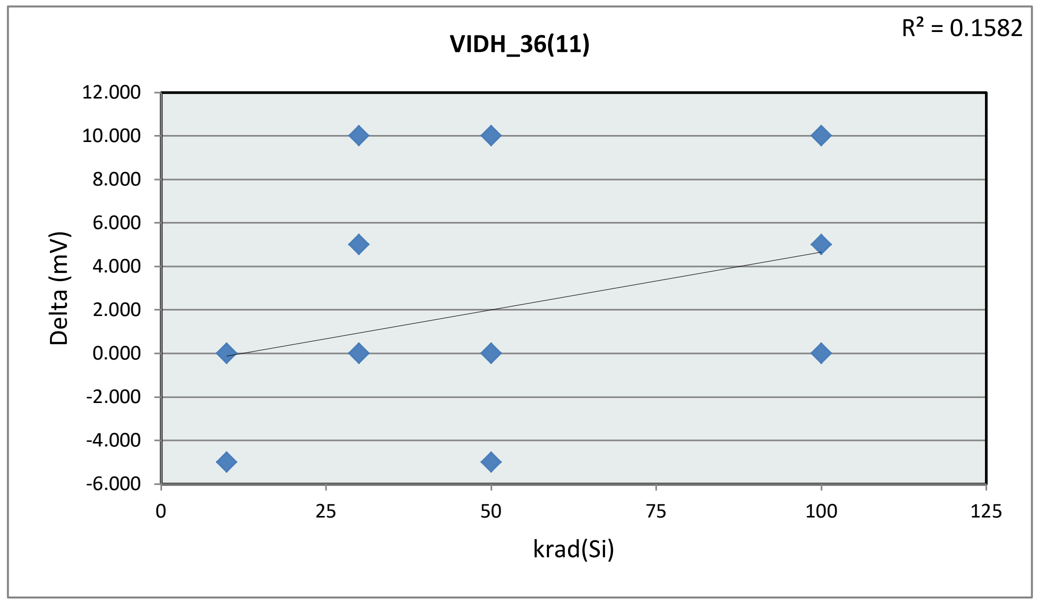


	DVTH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	15.000	10.000
Average	26.875	15.000	25.625	15.625
Max	40.000	20.000	40.000	25.000
UL	150.000	150.000	150.000	150.000

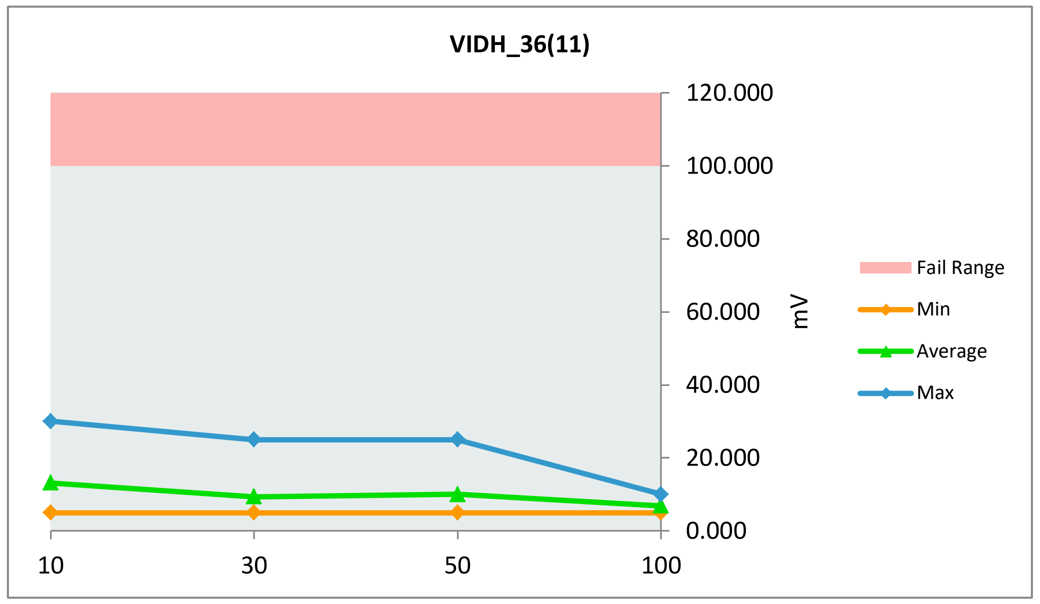


LDR Biased TID Report
SN55LVCP22A-SP

		VIDH_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	5.000	5.000	0.000
10	5	5.000	5.000	0.000
10	7	5.000	5.000	0.000
10	11	20.000	25.000	-5.000
10	15	5.000	5.000	0.000
10	20	25.000	30.000	-5.000
10	21	15.000	15.000	0.000
10	24	15.000	15.000	0.000
30	1	5.000	5.000	0.000
30	5	5.000	5.000	0.000
30	7	5.000	5.000	0.000
30	11	20.000	15.000	5.000
30	15	5.000	5.000	0.000
30	20	25.000	25.000	0.000
30	21	15.000	10.000	5.000
30	24	15.000	5.000	10.000
50	1	5.000	5.000	0.000
50	5	5.000	5.000	0.000
50	7	5.000	5.000	0.000
50	11	20.000	25.000	-5.000
50	15	5.000	5.000	0.000
50	20	25.000	25.000	0.000
50	21	15.000	5.000	10.000
50	24	15.000	5.000	10.000
100	3	20.000	10.000	10.000
100	8	5.000	5.000	0.000
100	12	5.000	5.000	0.000
100	13	5.000	5.000	0.000
100	16	5.000	5.000	0.000
100	17	15.000	10.000	5.000
100	18	15.000	5.000	10.000
100	19	20.000	10.000	10.000
	Max	25.000	30.000	10.000
	Average	11.719	9.844	1.875
	Min	5.000	5.000	-5.000
	Std Dev	7.363	7.776	4.535

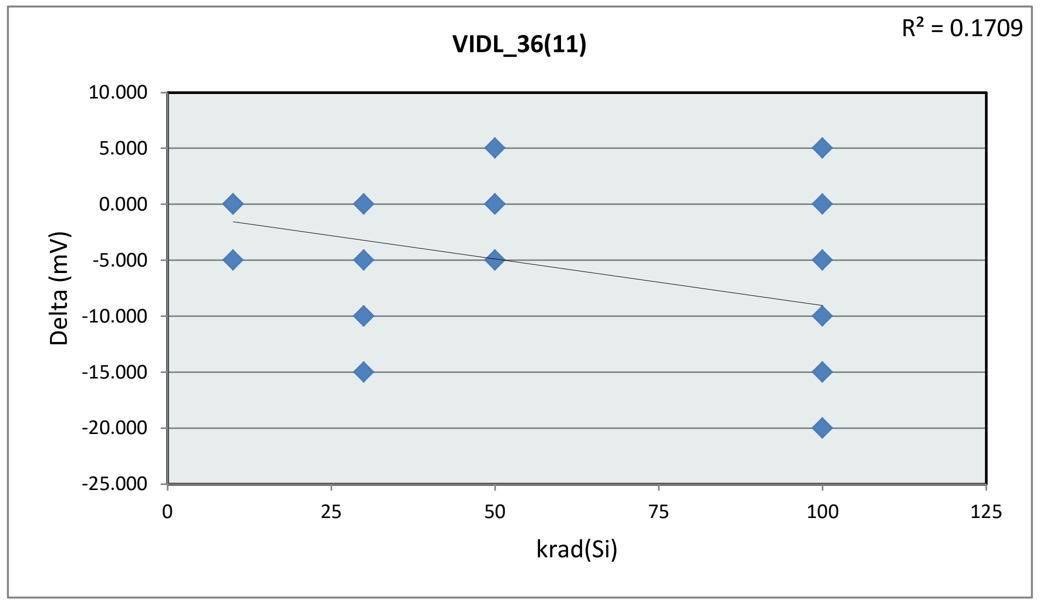


	VIDH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	13.125	9.375	10.000	6.875
Max	30.000	25.000	25.000	10.000
UL	100.000	100.000	100.000	100.000

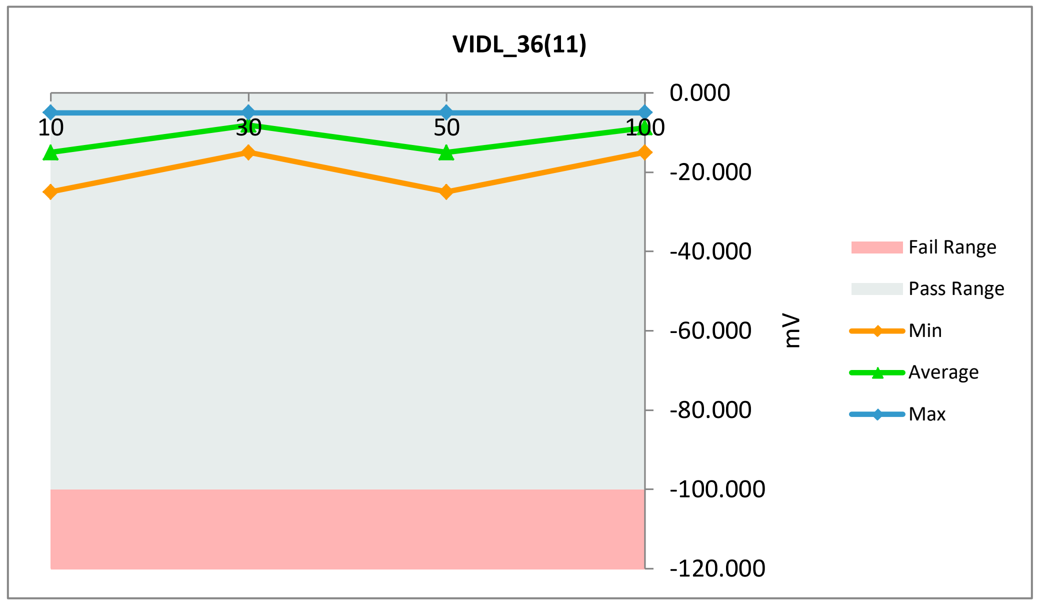


LDR Biased TID Report
SN55LVCP22A-SP

		VIDL_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-25.000	-25.000	0.000
10	5	-20.000	-20.000	0.000
10	7	-15.000	-15.000	0.000
10	11	-15.000	-15.000	0.000
10	15	-15.000	-15.000	0.000
10	20	-5.000	-5.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-25.000	-20.000	-5.000
30	1	-25.000	-15.000	-10.000
30	5	-20.000	-10.000	-10.000
30	7	-15.000	-10.000	-5.000
30	11	-15.000	-5.000	-10.000
30	15	-15.000	-5.000	-10.000
30	20	-5.000	-5.000	0.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-10.000	-15.000
50	1	-25.000	-25.000	0.000
50	5	-20.000	-20.000	0.000
50	7	-15.000	-10.000	-5.000
50	11	-15.000	-15.000	0.000
50	15	-15.000	-15.000	0.000
50	20	-5.000	-5.000	0.000
50	21	-5.000	-10.000	5.000
50	24	-25.000	-20.000	-5.000
100	3	-15.000	-5.000	-10.000
100	8	-30.000	-10.000	-20.000
100	12	-25.000	-5.000	-20.000
100	13	-25.000	-10.000	-15.000
100	16	-20.000	-15.000	-5.000
100	17	-5.000	-5.000	0.000
100	18	-5.000	-10.000	5.000
100	19	-25.000	-10.000	-15.000
	Max	-5.000	-5.000	5.000
	Average	-16.406	-11.719	-4.688
	Min	-30.000	-25.000	-20.000
	Std Dev	7.955	6.171	6.832

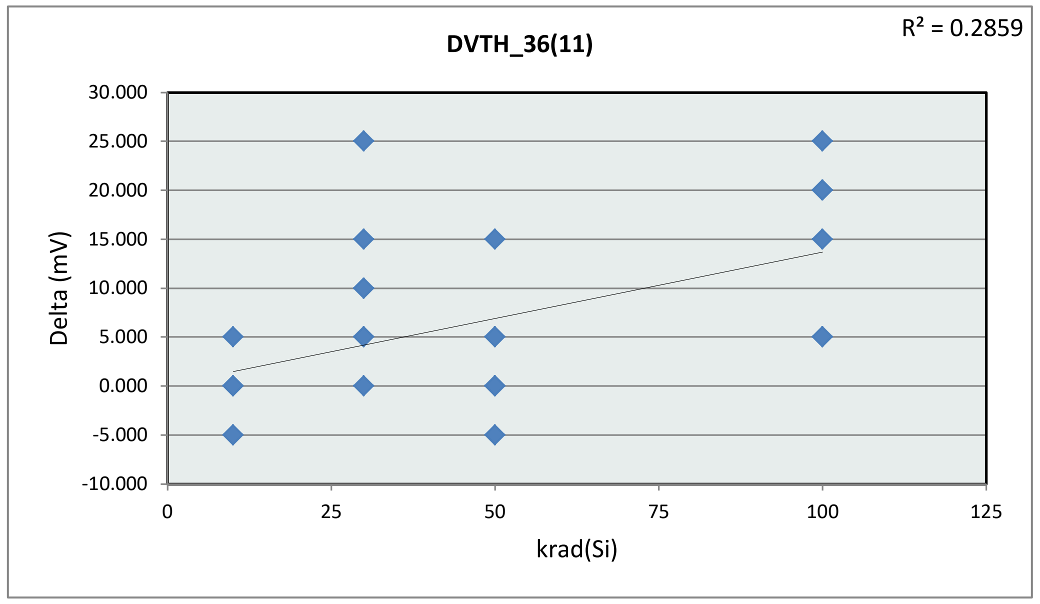


	VIDL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-15.000	-25.000	-15.000
Average	-15.000	-8.125	-15.000	-8.750
Max	-5.000	-5.000	-5.000	-5.000
UL				

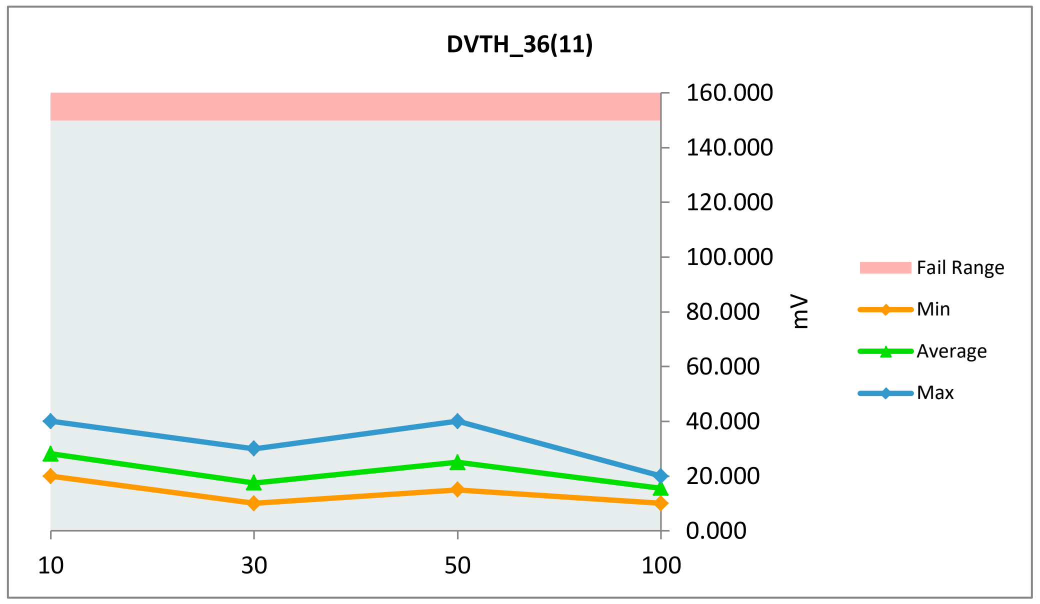


LDR Biased TID Report
SN55LVCP22A-SP

		DVTH_36(11)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	30.000	30.000	0.000
10	5	25.000	25.000	0.000
10	7	20.000	20.000	0.000
10	11	35.000	40.000	-5.000
10	15	20.000	20.000	0.000
10	20	30.000	35.000	-5.000
10	21	20.000	20.000	0.000
10	24	40.000	35.000	5.000
30	1	30.000	20.000	10.000
30	5	25.000	15.000	10.000
30	7	20.000	15.000	5.000
30	11	35.000	20.000	15.000
30	15	20.000	10.000	10.000
30	20	30.000	30.000	0.000
30	21	20.000	15.000	5.000
30	24	40.000	15.000	25.000
50	1	30.000	30.000	0.000
50	5	25.000	25.000	0.000
50	7	20.000	15.000	5.000
50	11	35.000	40.000	-5.000
50	15	20.000	20.000	0.000
50	20	30.000	30.000	0.000
50	21	20.000	15.000	5.000
50	24	40.000	25.000	15.000
100	3	35.000	15.000	20.000
100	8	35.000	15.000	20.000
100	12	30.000	10.000	20.000
100	13	30.000	15.000	15.000
100	16	25.000	20.000	5.000
100	17	20.000	15.000	5.000
100	18	20.000	15.000	5.000
100	19	45.000	20.000	25.000
	Max	45.000	40.000	25.000
	Average	28.125	21.563	6.563
	Min	20.000	10.000	-5.000
	Std Dev	7.487	8.273	8.654

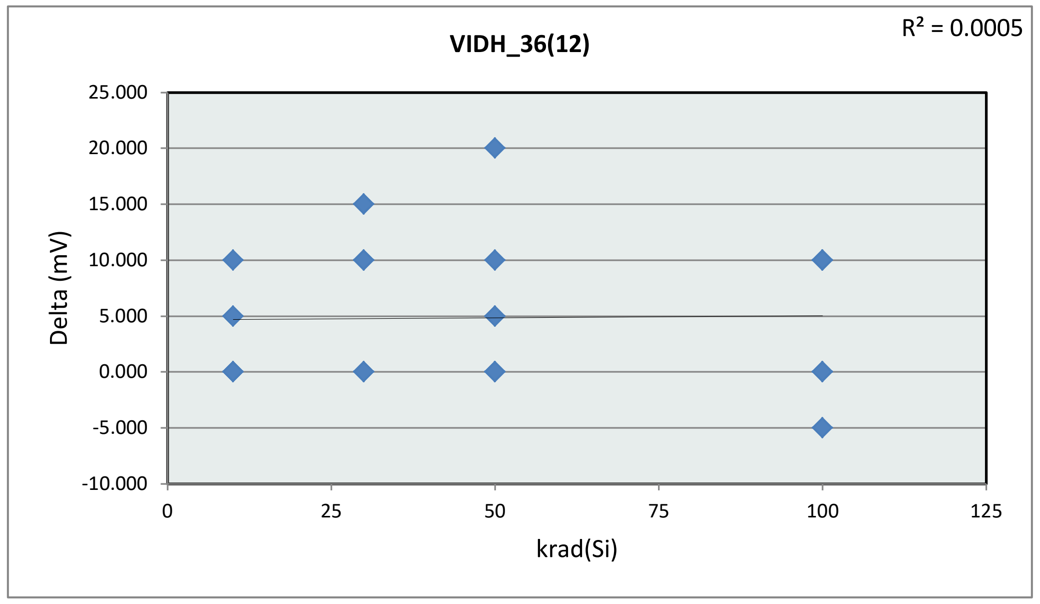


	DVTH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	15.000	10.000
Average	28.125	17.500	25.000	15.625
Max	40.000	30.000	40.000	20.000
UL	150.000	150.000	150.000	150.000

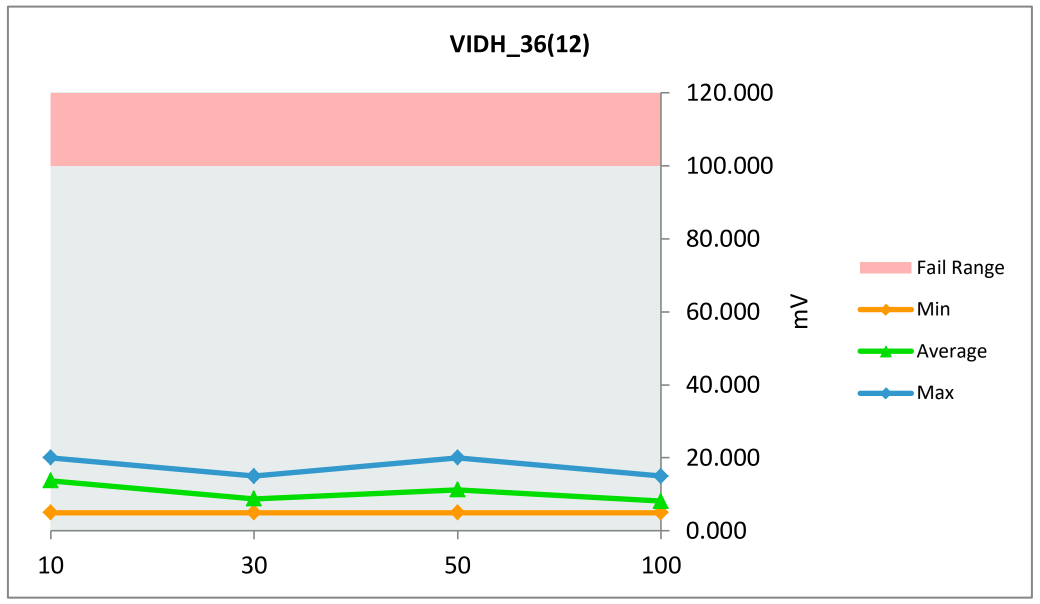


LDR Biased TID Report
SN55LVCP22A-SP

		VIDH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	25.000	20.000	5.000
10	5	5.000	5.000	0.000
10	7	15.000	15.000	0.000
10	11	25.000	20.000	5.000
10	15	5.000	5.000	0.000
10	20	20.000	20.000	0.000
10	21	20.000	20.000	0.000
10	24	15.000	5.000	10.000
30	1	25.000	10.000	15.000
30	5	5.000	5.000	0.000
30	7	15.000	15.000	0.000
30	11	25.000	10.000	15.000
30	15	5.000	5.000	0.000
30	20	20.000	10.000	10.000
30	21	20.000	10.000	10.000
30	24	15.000	5.000	10.000
50	1	25.000	20.000	5.000
50	5	5.000	5.000	0.000
50	7	15.000	15.000	0.000
50	11	25.000	5.000	20.000
50	15	5.000	5.000	0.000
50	20	20.000	20.000	0.000
50	21	20.000	15.000	5.000
50	24	15.000	5.000	10.000
100	3	5.000	5.000	0.000
100	8	5.000	5.000	0.000
100	12	5.000	10.000	-5.000
100	13	25.000	15.000	10.000
100	16	5.000	5.000	0.000
100	17	15.000	5.000	10.000
100	18	20.000	10.000	10.000
100	19	20.000	10.000	10.000
	Max	25.000	20.000	20.000
	Average	15.313	10.469	4.844
	Min	5.000	5.000	-5.000
	Std Dev	7.822	5.869	6.022



	VIDH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	13.750	8.750	11.250	8.125
Max	20.000	15.000	20.000	15.000
UL	100.000	100.000	100.000	100.000



LDR Biased TID Report
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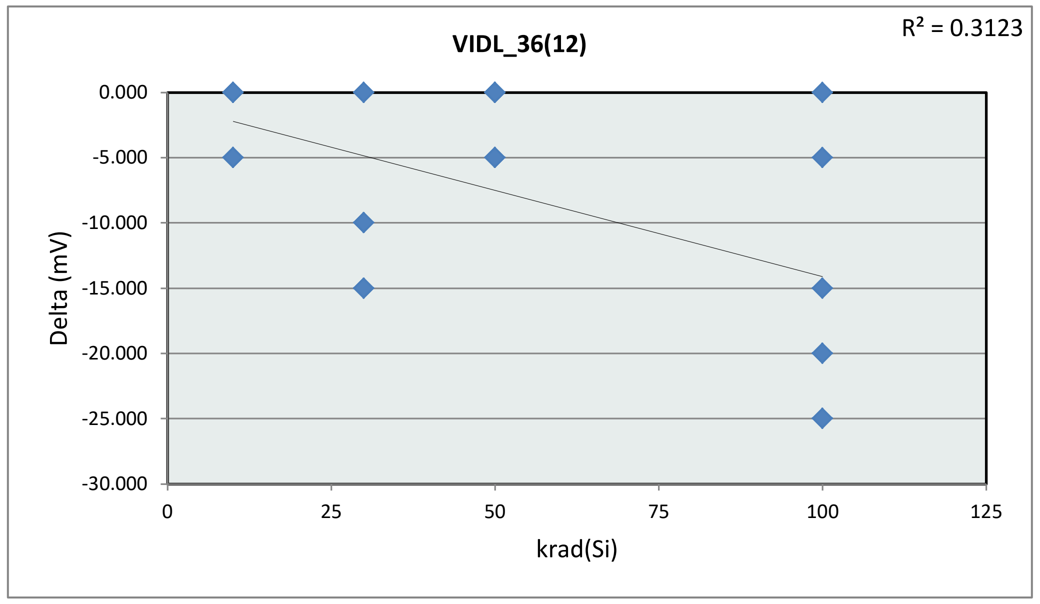
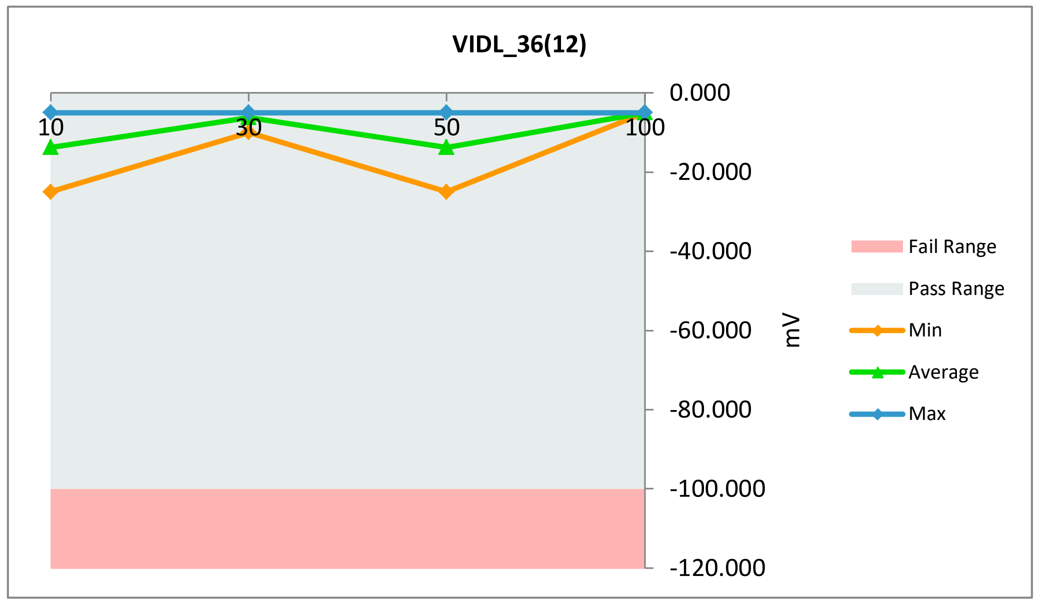
		VIDL_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-15.000	-10.000	-5.000
10	5	-25.000	-20.000	-5.000
10	7	-5.000	-5.000	0.000
10	11	-20.000	-20.000	0.000
10	15	-15.000	-10.000	-5.000
10	20	-15.000	-15.000	0.000
10	21	-5.000	-5.000	0.000
10	24	-25.000	-25.000	0.000
30	1	-15.000	-5.000	-10.000
30	5	-25.000	-10.000	-15.000
30	7	-5.000	-5.000	0.000
30	11	-20.000	-5.000	-15.000
30	15	-15.000	-5.000	-10.000
30	20	-15.000	-5.000	-10.000
30	21	-5.000	-5.000	0.000
30	24	-25.000	-10.000	-15.000
50	1	-15.000	-10.000	-5.000
50	5	-25.000	-20.000	-5.000
50	7	-5.000	-5.000	0.000
50	11	-20.000	-20.000	0.000
50	15	-15.000	-10.000	-5.000
50	20	-15.000	-15.000	0.000
50	21	-5.000	-5.000	0.000
50	24	-25.000	-25.000	0.000
100	3	-25.000	-5.000	-20.000
100	8	-30.000	-5.000	-25.000
100	12	-25.000	-5.000	-20.000
100	13	-20.000	-5.000	-15.000
100	16	-20.000	-5.000	-15.000
100	17	-10.000	-5.000	-5.000
100	18	-5.000	-5.000	0.000
100	19	-30.000	-5.000	-25.000
	Max	-5.000	-5.000	0.000
	Average	-16.875	-9.688	-7.188
	Min	-30.000	-25.000	-25.000
	Std Dev	8.007	6.591	8.026



	VIDL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-25.000	-10.000	-25.000	-5.000
Average	-13.750	-6.250	-13.750	-5.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



LDR Biased TID Report
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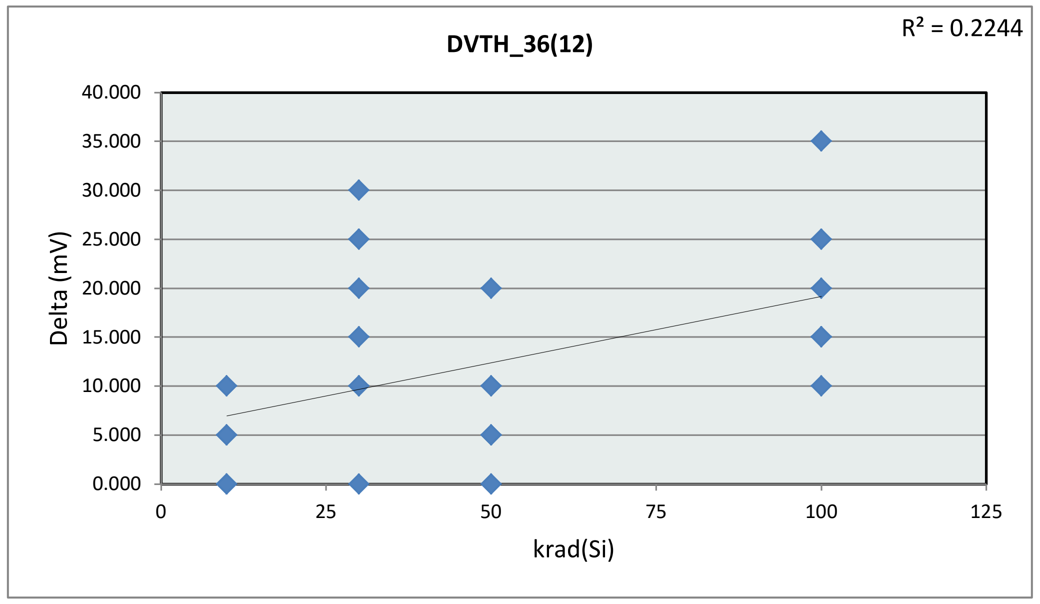
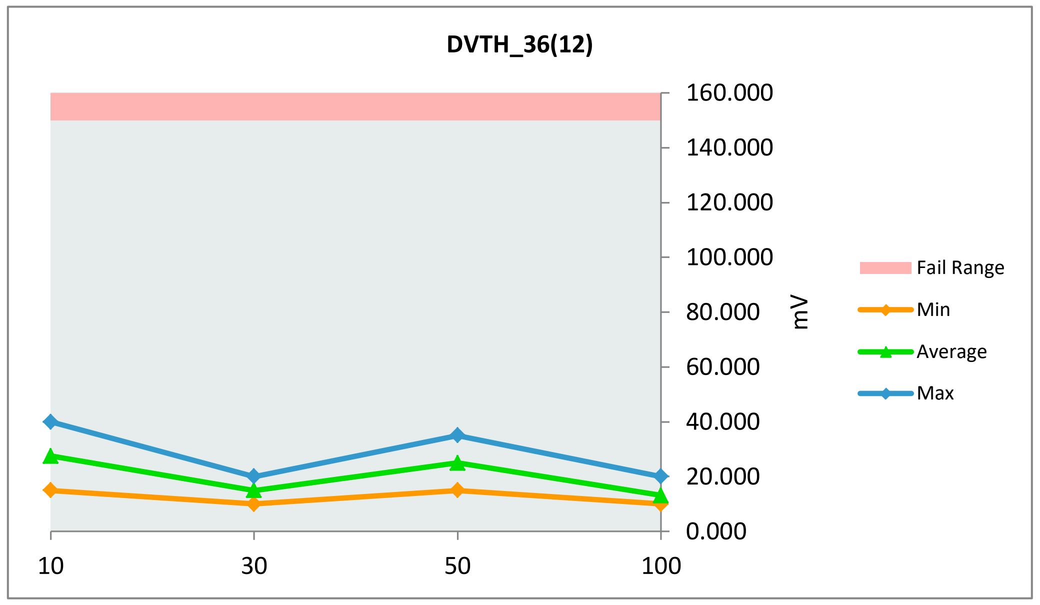
	DVTH_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	40.000	30.000	10.000
10	5	30.000	25.000	5.000
10	7	20.000	20.000	0.000
10	11	45.000	40.000	5.000
10	15	20.000	15.000	5.000
10	20	35.000	35.000	0.000
10	21	25.000	25.000	0.000
10	24	40.000	30.000	10.000
30	1	40.000	15.000	25.000
30	5	30.000	15.000	15.000
30	7	20.000	20.000	0.000
30	11	45.000	15.000	30.000
30	15	20.000	10.000	10.000
30	20	35.000	15.000	20.000
30	21	25.000	15.000	10.000
30	24	40.000	15.000	25.000
50	1	40.000	30.000	10.000
50	5	30.000	25.000	5.000
50	7	20.000	20.000	0.000
50	11	45.000	25.000	20.000
50	15	20.000	15.000	5.000
50	20	35.000	35.000	0.000
50	21	25.000	20.000	5.000
50	24	40.000	30.000	10.000
100	3	30.000	10.000	20.000
100	8	35.000	10.000	25.000
100	12	30.000	15.000	15.000
100	13	45.000	20.000	25.000
100	16	25.000	10.000	15.000
100	17	25.000	10.000	15.000
100	18	25.000	15.000	10.000
100	19	50.000	15.000	35.000
	Max	50.000	40.000	35.000
	Average	32.188	20.156	12.031
	Min	20.000	10.000	0.000
	Std Dev	9.153	8.278	9.743

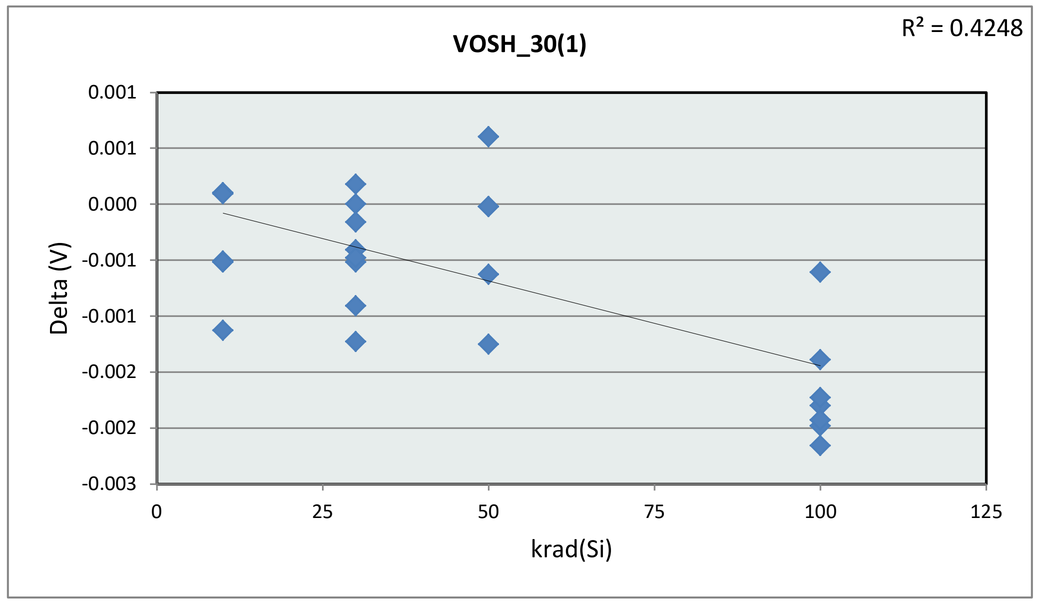


	DVTH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	15.000	10.000
Average	27.500	15.000	25.000	13.125
Max	40.000	20.000	35.000	20.000
UL	150.000	150.000	150.000	150.000

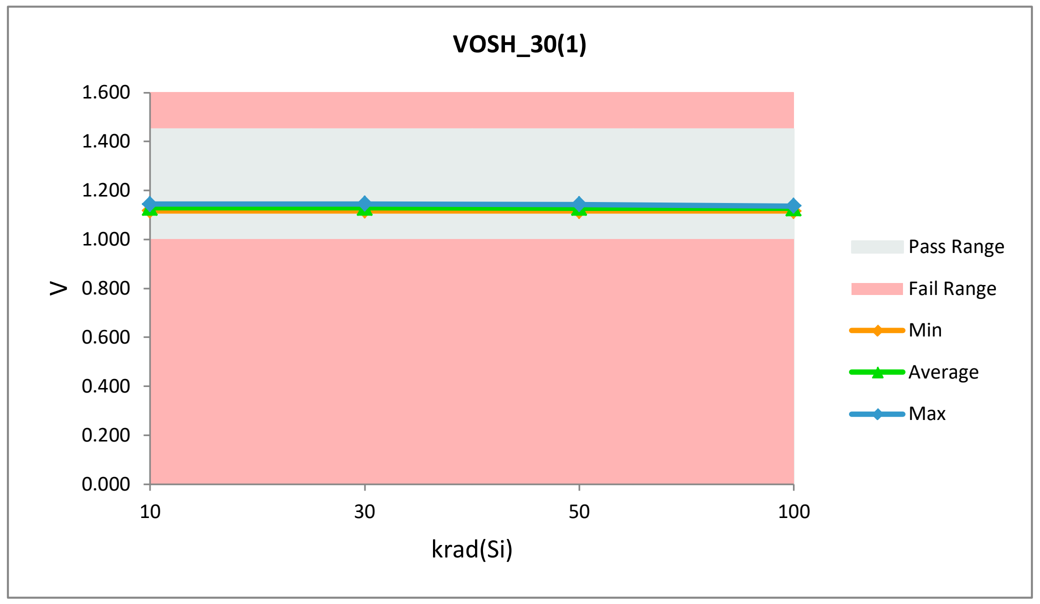


LDR Biased TID Report
SN55LVCP22A-SP

		VOSH_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.131	1.132	-0.001
10	5	1.139	1.140	-0.001
10	7	1.144	1.144	0.000
10	11	1.116	1.116	0.000
10	15	1.124	1.124	-0.001
10	20	1.121	1.121	0.000
10	21	1.128	1.128	-0.001
10	24	1.122	1.123	-0.001
30	1	1.131	1.131	0.000
30	5	1.139	1.139	0.000
30	7	1.144	1.145	-0.001
30	11	1.116	1.117	-0.001
30	15	1.124	1.124	0.000
30	20	1.121	1.122	-0.001
30	21	1.128	1.128	0.000
30	24	1.122	1.122	0.000
50	1	1.131	1.131	0.000
50	5	1.139	1.139	0.000
50	7	1.144	1.143	0.001
50	11	1.116	1.116	0.001
50	15	1.124	1.124	0.000
50	20	1.121	1.122	-0.001
50	21	1.128	1.128	-0.001
50	24	1.122	1.122	0.000
100	3	1.114	1.116	-0.002
100	8	1.131	1.133	-0.002
100	12	1.125	1.127	-0.002
100	13	1.121	1.122	-0.001
100	16	1.124	1.126	-0.002
100	17	1.134	1.136	-0.002
100	18	1.125	1.127	-0.002
100	19	1.123	1.124	-0.001
	Max	1.144	1.145	0.001
	Average	1.127	1.128	-0.001
	Min	1.114	1.116	-0.002
	Std Dev	0.008	0.008	0.001

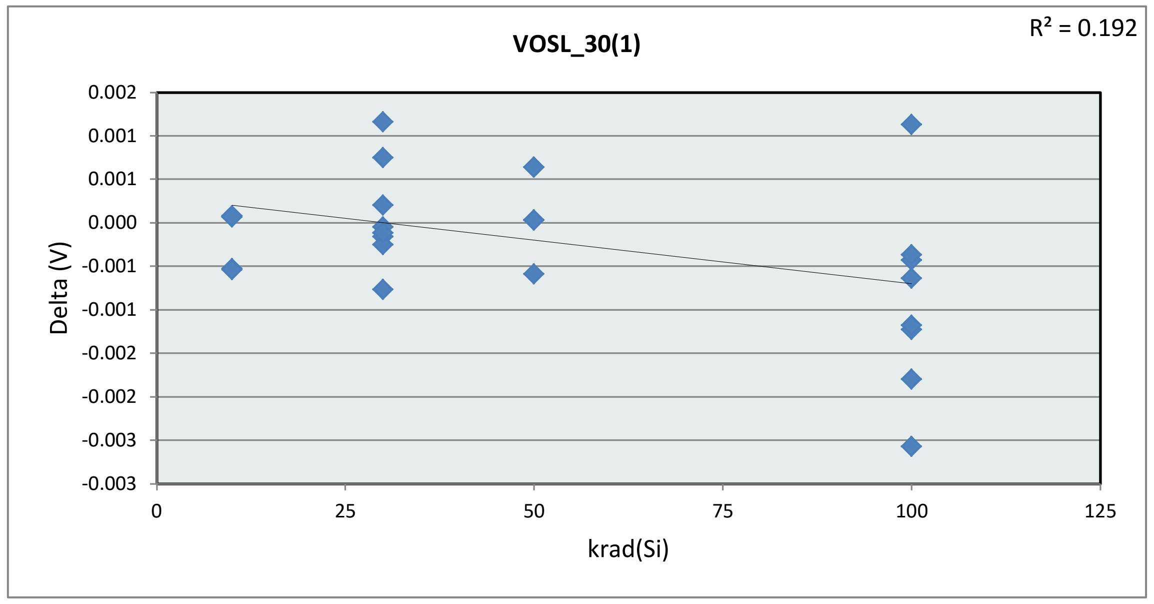


	VOSH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.116	1.117	1.116	1.116
Average	1.128	1.129	1.128	1.126
Max	1.144	1.145	1.143	1.136
UL	1.450	1.450	1.450	1.450

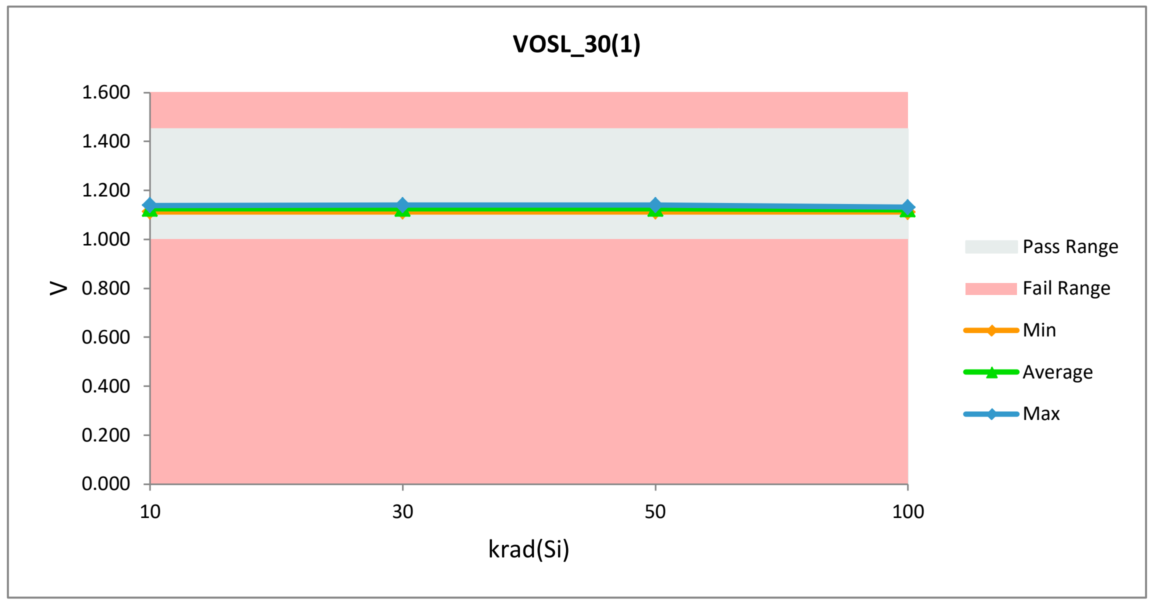


LDR Biased TID Report
SN55LVCP22A-SP

		VOSL_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.127	1.127	0.000
10	5	1.136	1.137	-0.001
10	7	1.139	1.139	0.000
10	11	1.113	1.113	0.000
10	15	1.120	1.120	0.000
10	20	1.118	1.118	0.000
10	21	1.124	1.124	0.000
10	24	1.118	1.118	-0.001
30	1	1.127	1.127	0.000
30	5	1.136	1.135	0.001
30	7	1.139	1.140	-0.001
30	11	1.113	1.113	0.000
30	15	1.120	1.120	0.000
30	20	1.118	1.118	0.000
30	21	1.124	1.124	0.000
30	24	1.118	1.117	0.001
50	1	1.127	1.126	0.001
50	5	1.136	1.136	0.001
50	7	1.139	1.139	0.000
50	11	1.113	1.113	0.000
50	15	1.120	1.120	0.001
50	20	1.118	1.118	0.000
50	21	1.124	1.124	-0.001
50	24	1.118	1.118	0.000
100	3	1.110	1.111	-0.001
100	8	1.128	1.128	0.000
100	12	1.121	1.124	-0.003
100	13	1.117	1.116	0.001
100	16	1.120	1.122	-0.002
100	17	1.131	1.131	0.000
100	18	1.121	1.122	-0.001
100	19	1.118	1.119	-0.001
	Max	1.139	1.140	0.001
	Average	1.123	1.124	0.000
	Min	1.110	1.111	-0.003
	Std Dev	0.008	0.008	0.001



	VOSL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.113	1.113	1.113	1.111
Average	1.124	1.124	1.124	1.122
Max	1.139	1.140	1.139	1.131
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
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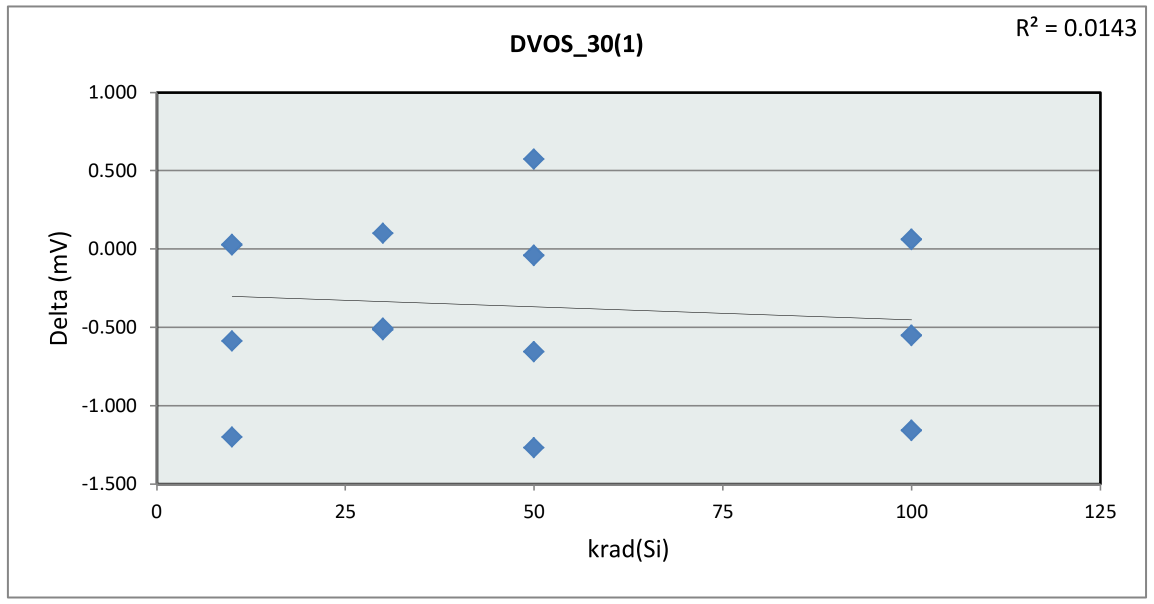
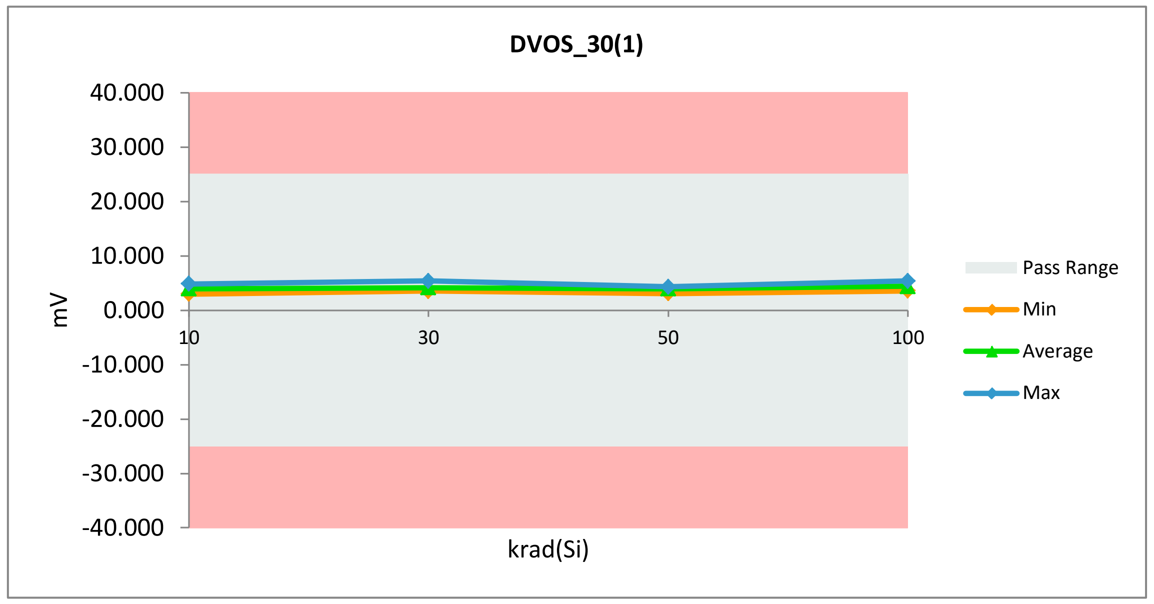
	DVOS_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.639	4.840	-1.201
10	5	3.026	3.000	0.026
10	7	4.867	4.841	0.026
10	11	3.639	3.612	0.026
10	15	3.638	4.225	-0.587
10	20	3.025	2.999	0.026
10	21	3.639	4.227	-0.588
10	24	4.252	4.225	0.027
30	1	3.639	4.152	-0.513
30	5	3.026	3.542	-0.516
30	7	4.867	5.375	-0.508
30	11	3.639	3.540	0.099
30	15	3.638	4.149	-0.511
30	20	3.025	3.539	-0.514
30	21	3.639	4.152	-0.513
30	24	4.252	4.760	-0.508
50	1	3.639	4.294	-0.655
50	5	3.026	3.681	-0.655
50	7	4.867	4.294	0.573
50	11	3.639	3.067	0.572
50	15	3.638	4.294	-0.656
50	20	3.025	4.294	-1.269
50	21	3.639	3.680	-0.041
50	24	4.252	4.294	-0.042
100	3	4.253	4.192	0.061
100	8	3.639	4.191	-0.552
100	12	3.638	3.579	0.059
100	13	4.252	5.410	-1.158
100	16	3.638	4.189	-0.551
100	17	3.639	4.192	-0.553
100	18	4.253	4.191	0.062
100	19	4.252	5.412	-1.160
	Max	4.867	5.412	0.573
	Average	3.773	4.139	-0.365
	Min	3.025	2.999	-1.269
	Std Dev	0.534	0.625	0.471



	DVOS_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.999	3.539	3.067	3.579
Average	3.996	4.151	3.987	4.420
Max	4.841	5.375	4.294	5.412
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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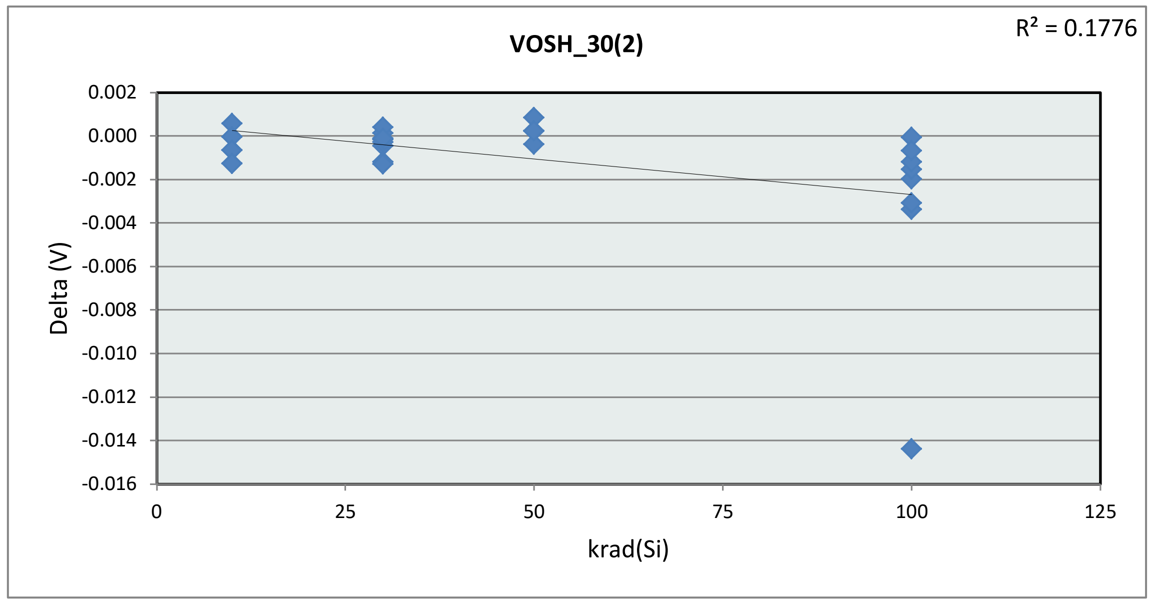
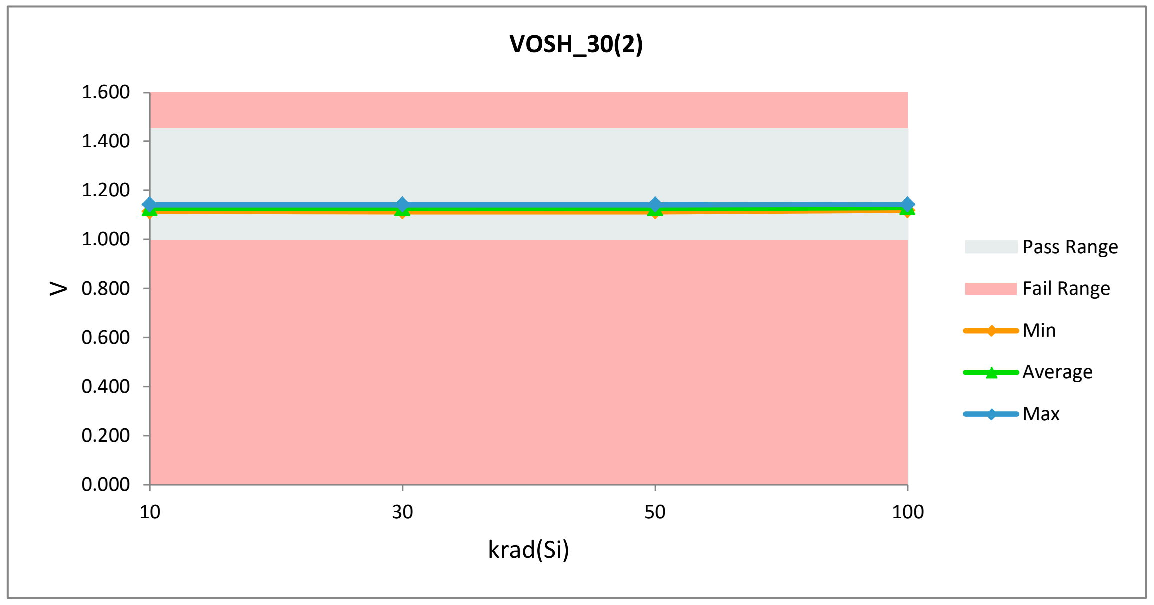
		VOSH_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.133	1.133	0.000
10	5	1.141	1.142	-0.001
10	7	1.126	1.126	0.001
10	11	1.118	1.118	-0.001
10	15	1.137	1.137	0.000
10	20	1.123	1.124	-0.001
10	21	1.123	1.123	-0.001
10	24	1.113	1.114	-0.001
30	1	1.133	1.133	0.000
30	5	1.141	1.141	0.000
30	7	1.126	1.126	0.000
30	11	1.118	1.119	-0.001
30	15	1.137	1.137	0.000
30	20	1.123	1.123	0.000
30	21	1.123	1.124	-0.001
30	24	1.113	1.113	0.000
50	1	1.133	1.132	0.000
50	5	1.141	1.141	0.000
50	7	1.126	1.126	0.001
50	11	1.118	1.118	0.000
50	15	1.137	1.136	0.001
50	20	1.123	1.122	0.000
50	21	1.123	1.123	0.000
50	24	1.113	1.113	0.000
100	3	1.127	1.129	-0.002
100	8	1.129	1.131	-0.002
100	12	1.118	1.119	-0.001
100	13	1.124	1.124	0.000
100	16	1.128	1.131	-0.003
100	17	1.132	1.135	-0.003
100	18	1.128	1.142	-0.014
100	19	1.131	1.132	-0.001
	Max	1.141	1.142	0.001
	Average	1.127	1.128	-0.001
	Min	1.113	1.113	-0.014
	Std Dev	0.008	0.009	0.003



	VOSH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.114	1.113	1.113	1.119
Average	1.127	1.127	1.126	1.130
Max	1.142	1.141	1.141	1.142
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
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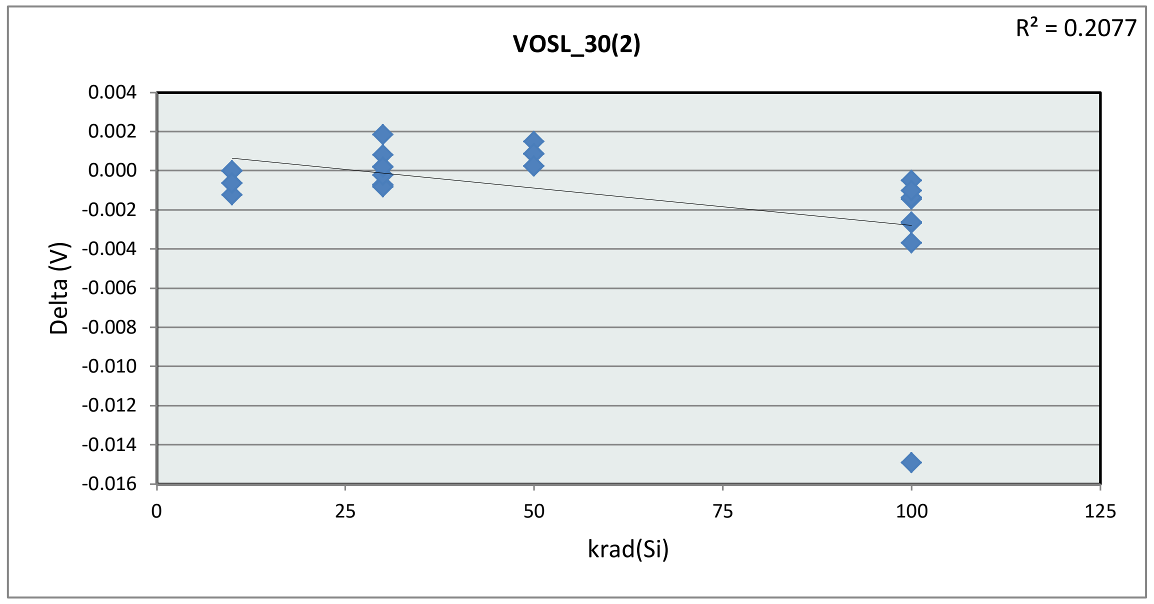
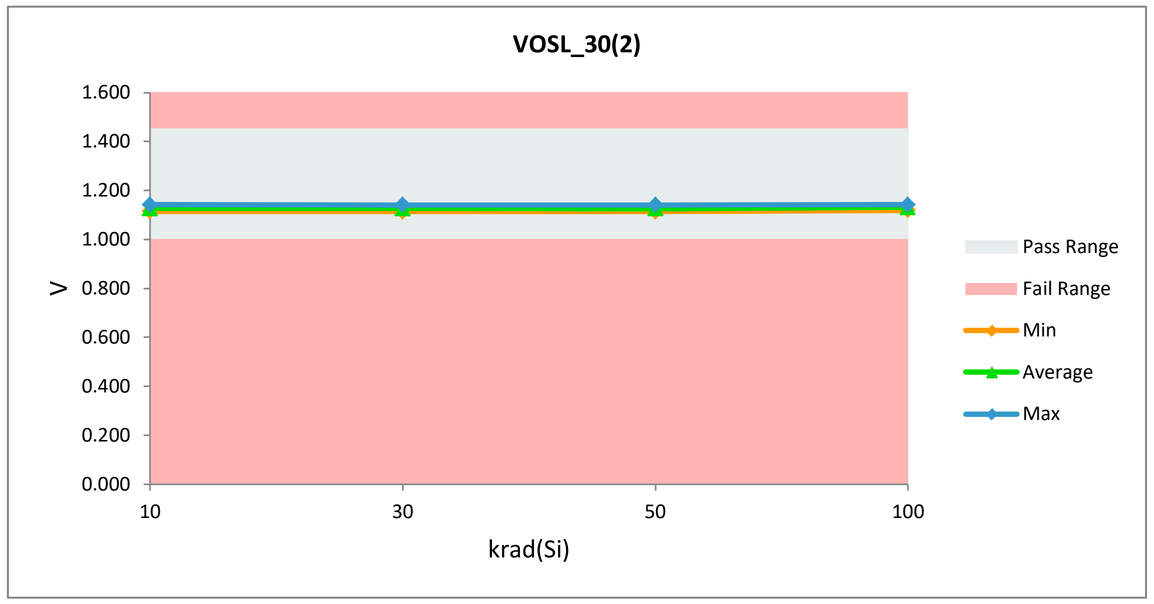
		VOSL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.133	1.133	0.000
10	5	1.142	1.142	0.000
10	7	1.126	1.126	0.000
10	11	1.117	1.118	-0.001
10	15	1.136	1.136	0.000
10	20	1.122	1.123	-0.001
10	21	1.123	1.123	-0.001
10	24	1.114	1.115	-0.001
30	1	1.133	1.133	0.000
30	5	1.142	1.141	0.001
30	7	1.126	1.124	0.002
30	11	1.117	1.118	-0.001
30	15	1.136	1.137	-0.001
30	20	1.122	1.123	-0.001
30	21	1.123	1.123	0.000
30	24	1.114	1.114	0.000
50	1	1.133	1.132	0.001
50	5	1.142	1.141	0.001
50	7	1.126	1.124	0.001
50	11	1.117	1.117	0.000
50	15	1.136	1.135	0.001
50	20	1.122	1.122	0.000
50	21	1.123	1.122	0.001
50	24	1.114	1.114	0.000
100	3	1.128	1.131	-0.003
100	8	1.130	1.131	-0.001
100	12	1.118	1.119	-0.001
100	13	1.125	1.126	-0.001
100	16	1.128	1.132	-0.004
100	17	1.131	1.134	-0.003
100	18	1.127	1.142	-0.015
100	19	1.132	1.133	-0.001
	Max	1.142	1.142	0.002
	Average	1.127	1.128	-0.001
	Min	1.114	1.114	-0.015
	Std Dev	0.008	0.009	0.003



	VOSL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.115	1.114	1.114	1.119
Average	1.127	1.127	1.126	1.131
Max	1.142	1.141	1.141	1.142
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
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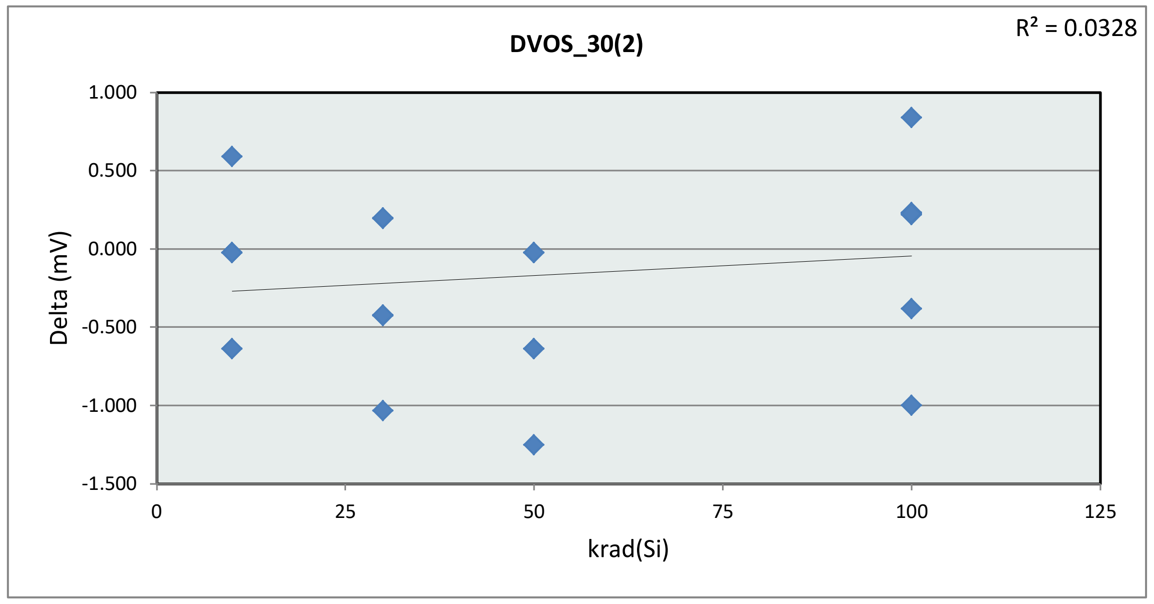
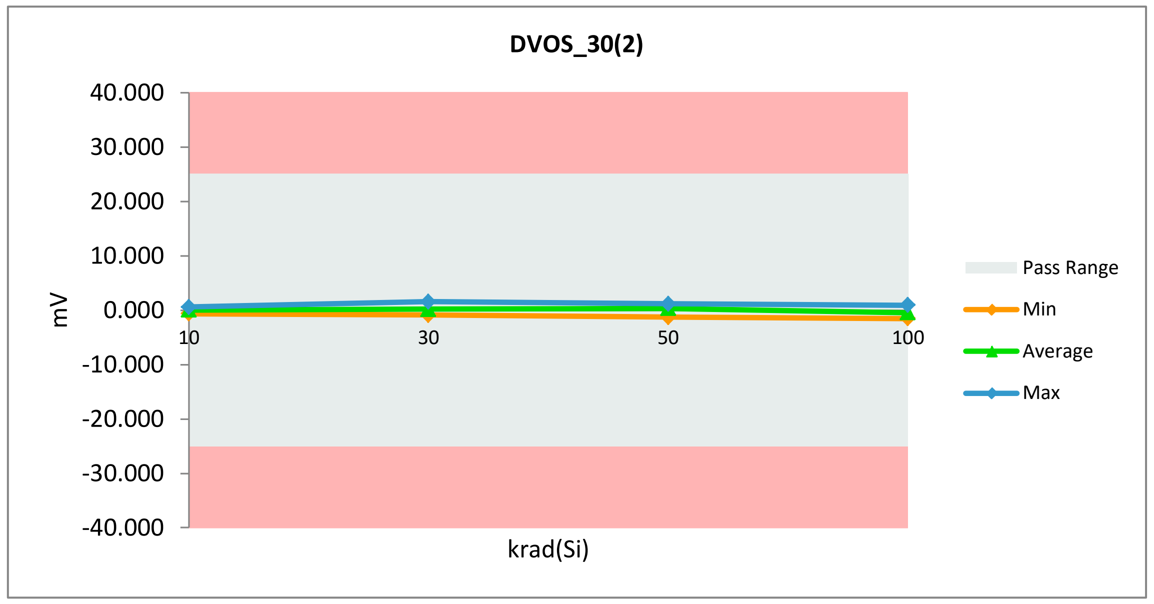
	DVOS_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.676	-0.652	-0.025
10	5	-0.675	-0.037	-0.638
10	7	0.552	-0.037	0.589
10	11	0.551	0.576	-0.025
10	15	0.550	0.575	-0.025
10	20	0.550	0.575	-0.025
10	21	-0.062	-0.037	-0.025
10	24	-1.291	-0.652	-0.639
30	1	-0.676	-0.251	-0.425
30	5	-0.675	-0.248	-0.427
30	7	0.552	1.584	-1.032
30	11	0.551	0.357	0.194
30	15	0.550	0.356	0.194
30	20	0.550	0.354	0.196
30	21	-0.062	0.363	-0.425
30	24	-1.291	-0.867	-0.424
50	1	-0.676	-0.037	-0.639
50	5	-0.675	-0.036	-0.639
50	7	0.552	1.191	-0.639
50	11	0.551	0.576	-0.026
50	15	0.550	0.576	-0.026
50	20	0.550	0.576	-0.026
50	21	-0.062	1.191	-1.253
50	24	-1.291	-1.265	-0.026
100	3	-1.290	-1.508	0.218
100	8	-0.063	-0.291	0.228
100	12	-0.677	0.323	-0.999
100	13	-0.678	-1.517	0.839
100	16	-0.677	-0.904	0.227
100	17	0.552	0.935	-0.384
100	18	0.551	0.321	0.230
100	19	-0.676	-0.900	0.223
	Max	0.552	1.584	0.839
	Average	-0.140	0.037	-0.177
	Min	-1.291	-1.517	-1.253
	Std Dev	0.693	0.773	0.474



	DVOS_30(2)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.652	-0.867	-1.265	-1.517
Average	0.039	0.206	0.346	-0.443
Max	0.576	1.584	1.191	0.935
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
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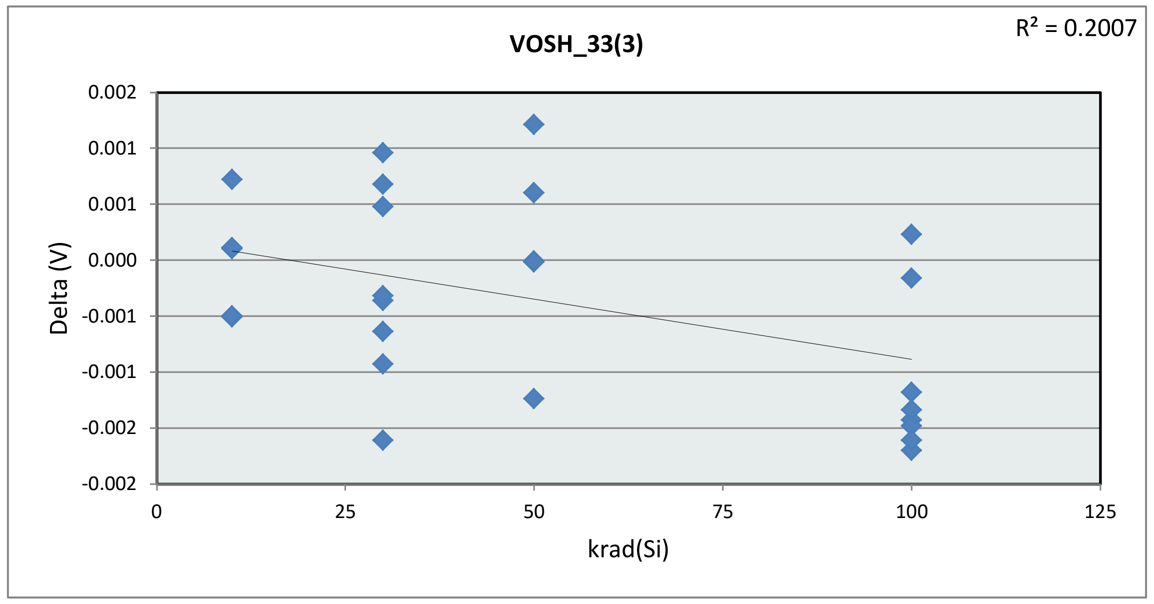
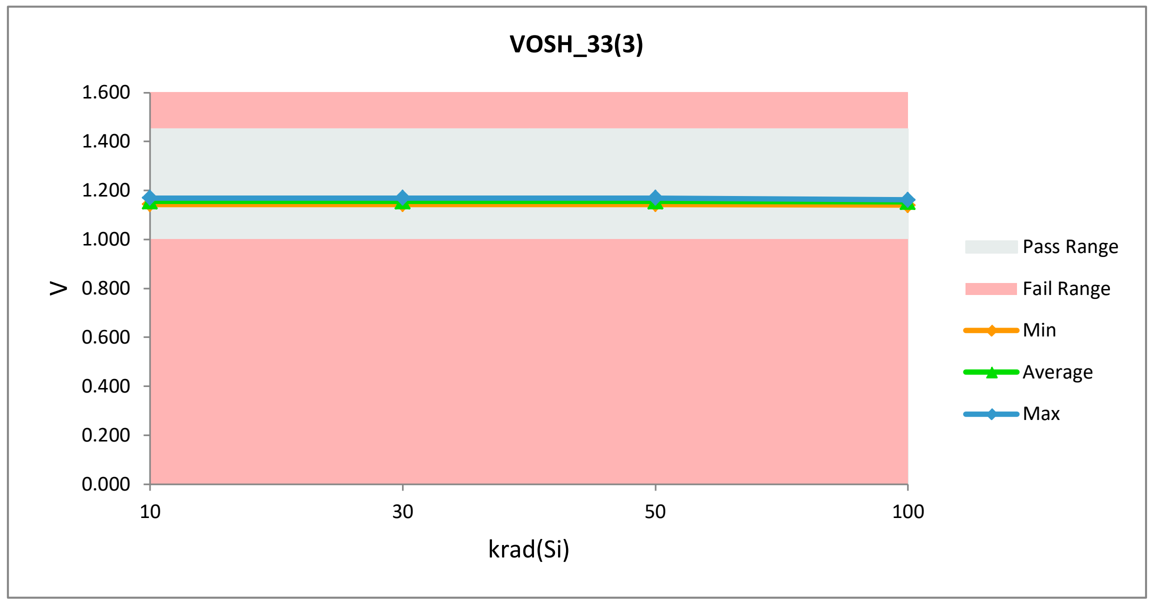
		VOSH_33(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.156	1.156	0.000
10	5	1.165	1.165	0.000
10	7	1.169	1.169	0.000
10	11	1.143	1.143	0.000
10	15	1.153	1.153	0.000
10	20	1.148	1.149	-0.001
10	21	1.152	1.153	0.000
10	24	1.153	1.152	0.001
30	1	1.156	1.157	-0.001
30	5	1.165	1.164	0.001
30	7	1.169	1.169	0.000
30	11	1.143	1.143	0.000
30	15	1.153	1.153	0.000
30	20	1.148	1.150	-0.002
30	21	1.152	1.153	-0.001
30	24	1.153	1.152	0.001
50	1	1.156	1.156	0.000
50	5	1.165	1.165	0.000
50	7	1.169	1.169	0.000
50	11	1.143	1.143	0.001
50	15	1.153	1.152	0.001
50	20	1.148	1.148	0.000
50	21	1.152	1.153	-0.001
50	24	1.153	1.151	0.001
100	3	1.139	1.140	-0.001
100	8	1.161	1.162	-0.001
100	12	1.153	1.155	-0.002
100	13	1.150	1.150	0.000
100	16	1.155	1.156	-0.001
100	17	1.159	1.160	-0.001
100	18	1.151	1.151	0.000
100	19	1.148	1.150	-0.002
	Max	1.169	1.169	0.001
	Average	1.154	1.154	0.000
	Min	1.139	1.140	-0.002
	Std Dev	0.008	0.008	0.001



	VOSH_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.143	1.143	1.143	1.140
Average	1.155	1.155	1.155	1.153
Max	1.169	1.169	1.169	1.162
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
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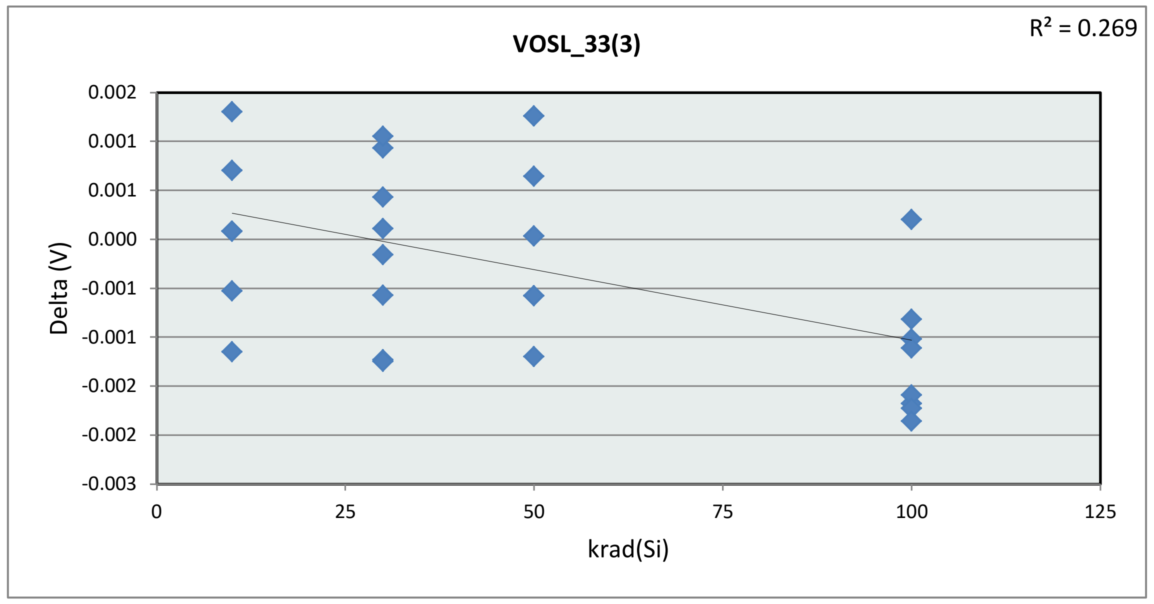
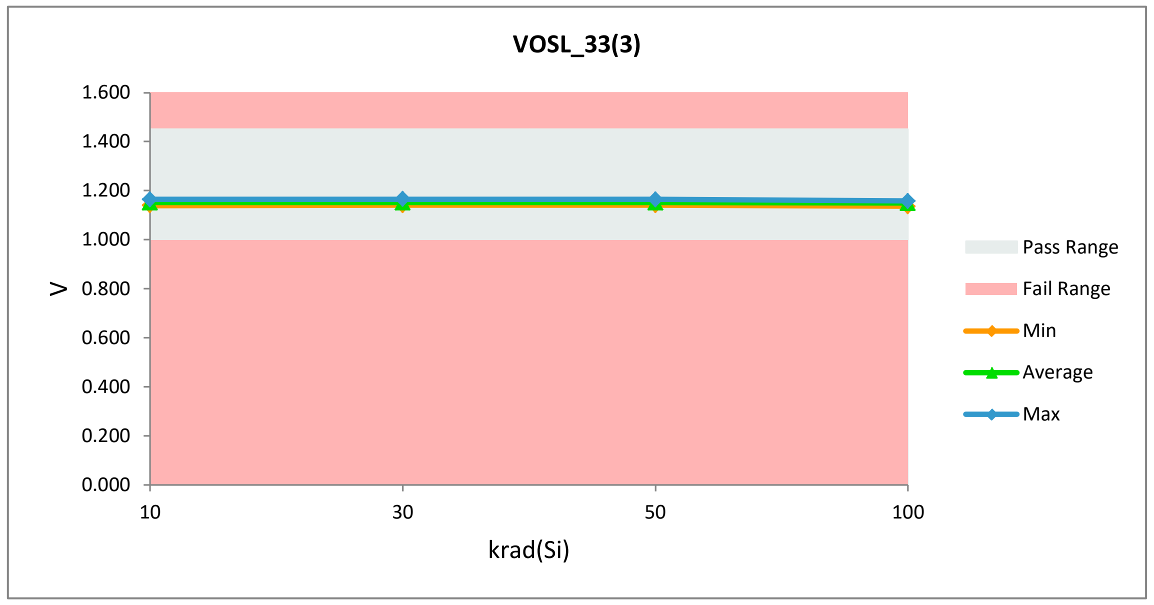
	VOSL_33(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.152	1.152	0.000
10	5	1.162	1.162	0.000
10	7	1.164	1.164	-0.001
10	11	1.140	1.140	0.000
10	15	1.149	1.148	0.001
10	20	1.145	1.146	-0.001
10	21	1.148	1.148	0.000
10	24	1.148	1.147	0.001
30	1	1.152	1.152	0.000
30	5	1.162	1.161	0.001
30	7	1.164	1.165	-0.001
30	11	1.140	1.140	0.000
30	15	1.149	1.148	0.001
30	20	1.145	1.146	-0.001
30	21	1.148	1.149	-0.001
30	24	1.148	1.148	0.000
50	1	1.152	1.152	0.000
50	5	1.162	1.161	0.001
50	7	1.164	1.164	0.000
50	11	1.140	1.140	-0.001
50	15	1.149	1.148	0.001
50	20	1.145	1.145	-0.001
50	21	1.148	1.150	-0.001
50	24	1.148	1.147	0.001
100	3	1.134	1.136	-0.002
100	8	1.156	1.158	-0.002
100	12	1.150	1.152	-0.002
100	13	1.146	1.147	-0.001
100	16	1.151	1.152	-0.001
100	17	1.155	1.156	-0.001
100	18	1.147	1.147	0.000
100	19	1.144	1.146	-0.002
	Max	1.164	1.165	0.001
	Average	1.150	1.151	0.000
	Min	1.134	1.136	-0.002
	Std Dev	0.008	0.007	0.001



	VOSL_33(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	1.45	V
Min Limit	1	V

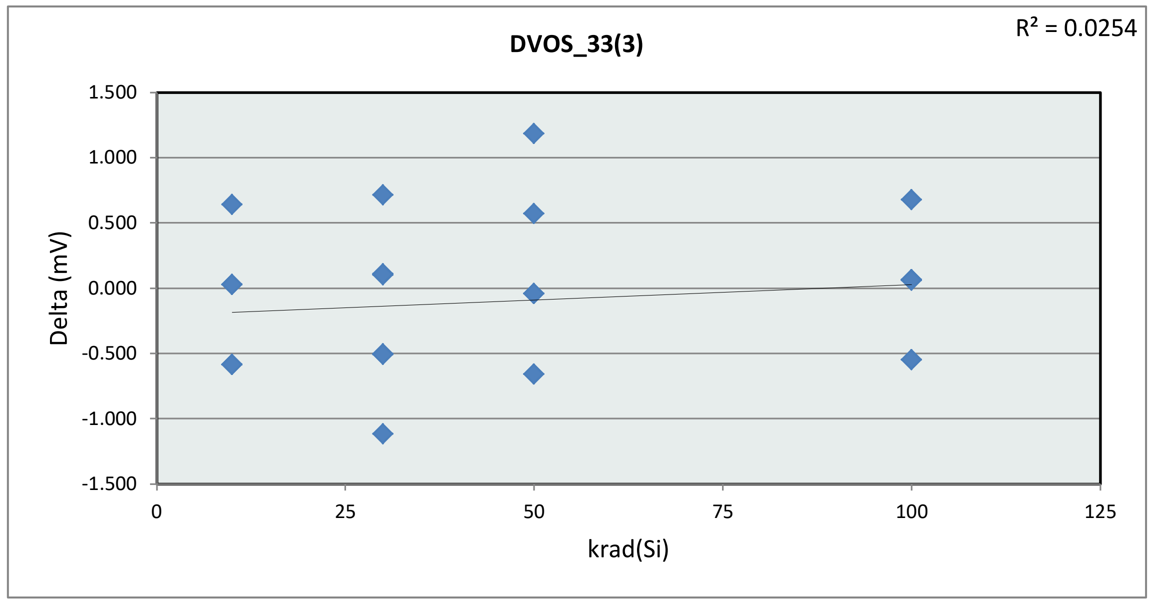
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.140	1.140	1.140	1.136
Average	1.151	1.151	1.151	1.149
Max	1.164	1.165	1.164	1.158
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
SN55LVCP22A-SP

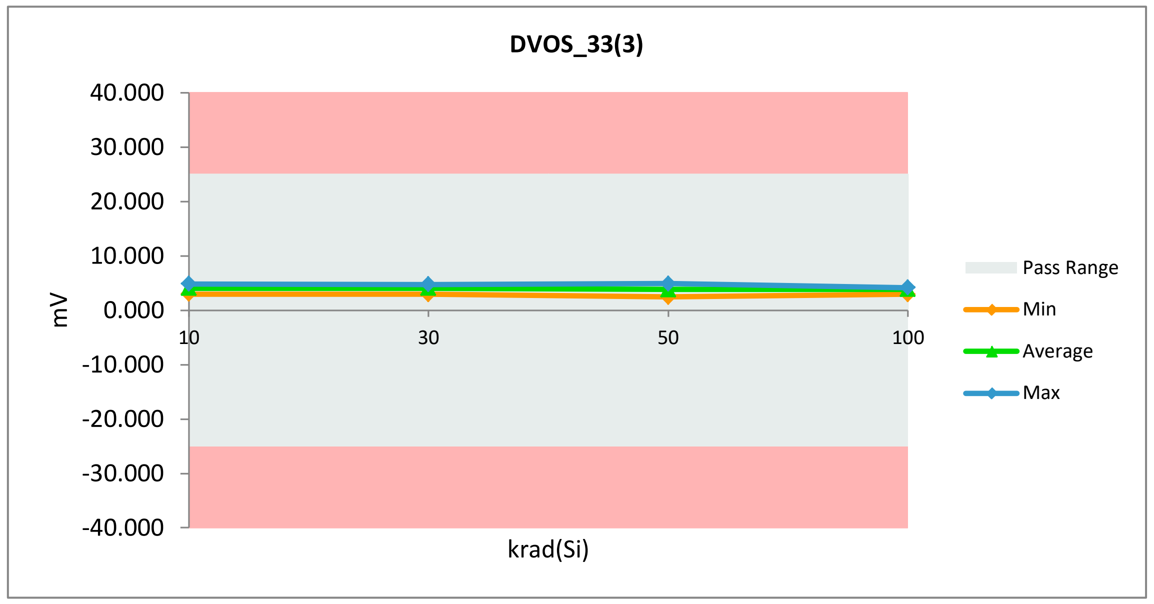
	DVOS_33(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	4.250	4.222	0.028
10	5	3.022	3.608	-0.586
10	7	4.864	4.836	0.028
10	11	3.636	3.609	0.028
10	15	3.636	4.223	-0.586
10	20	3.636	2.995	0.641
10	21	3.636	4.223	-0.586
10	24	4.250	4.836	-0.586
30	1	4.250	4.755	-0.505
30	5	3.022	3.532	-0.510
30	7	4.864	4.755	0.109
30	11	3.636	2.923	0.713
30	15	3.636	4.755	-1.119
30	20	3.636	3.534	0.102
30	21	3.636	4.145	-0.509
30	24	4.250	4.144	0.106
50	1	4.250	4.294	-0.044
50	5	3.022	3.680	-0.658
50	7	4.864	4.907	-0.044
50	11	3.636	2.453	1.183
50	15	3.636	4.294	-0.658
50	20	3.636	3.067	0.570
50	21	3.636	3.680	-0.044
50	24	4.250	4.294	-0.044
100	3	4.250	4.185	0.065
100	8	4.250	4.186	0.064
100	12	3.022	2.964	0.058
100	13	4.250	3.575	0.675
100	16	3.636	4.186	-0.550
100	17	3.636	3.575	0.061
100	18	3.637	4.185	-0.548
100	19	4.250	4.185	0.065
	Max	4.864	4.907	1.183
	Average	3.866	3.963	-0.096
	Min	3.022	2.453	-1.119
	Std Dev	0.511	0.630	0.499



	DVOS_33(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

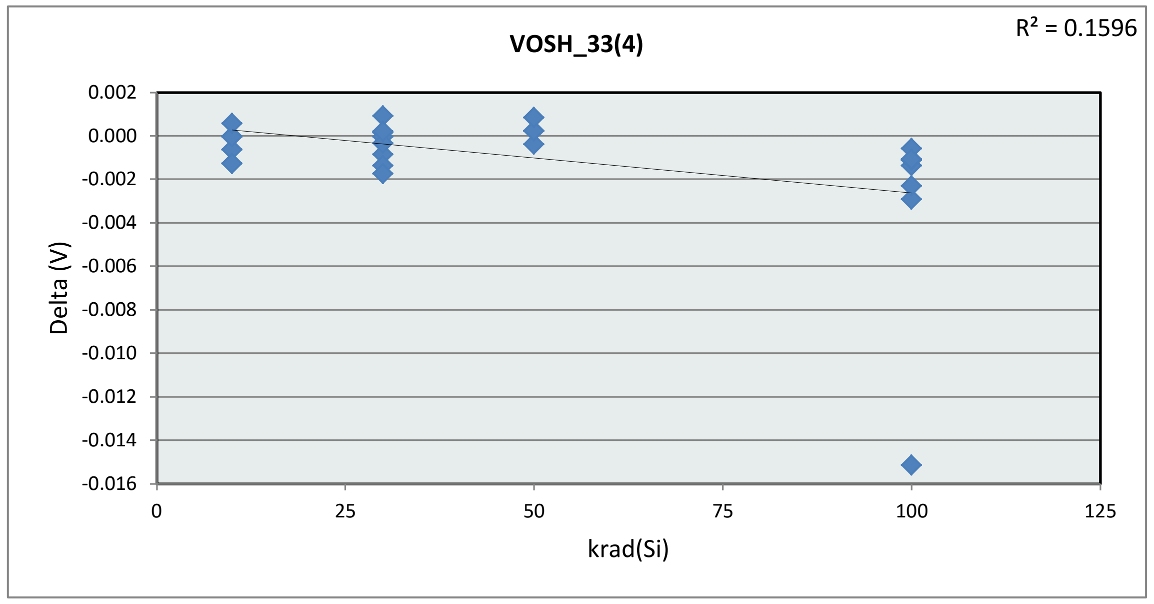
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.995	2.923	2.453	2.964
Average	4.069	4.068	3.834	3.880
Max	4.836	4.755	4.907	4.186
UL	25.000	25.000	25.000	25.000



LDR Biased TID Report
SN55LVCP22A-SP

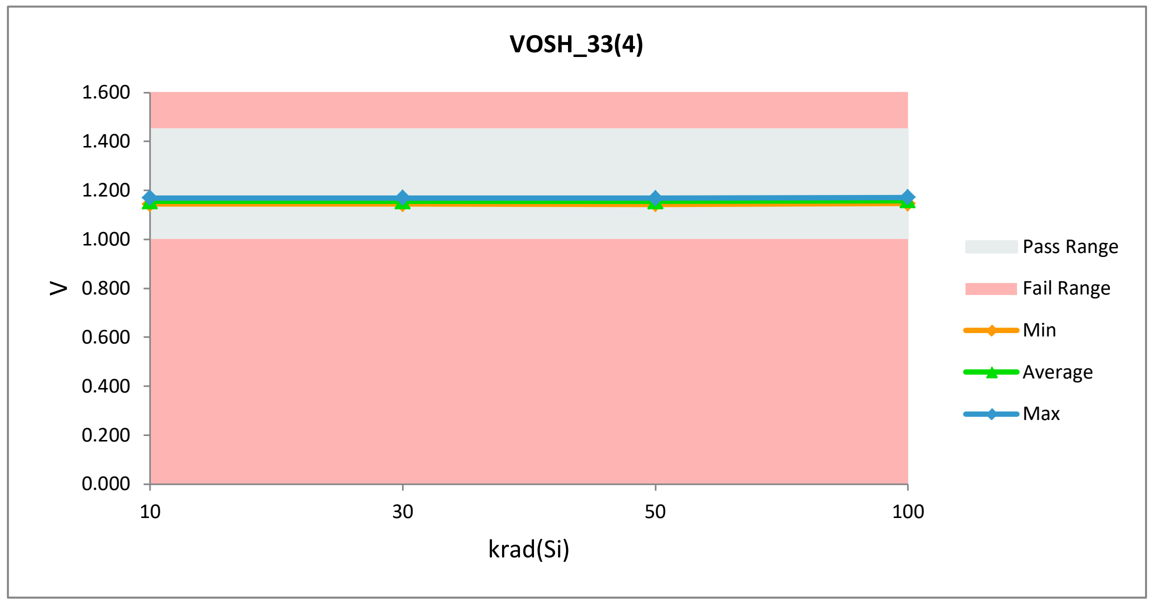
	VOSH_33(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.160	1.160	0.000
10	5	1.168	1.169	-0.001
10	7	1.151	1.151	0.000
10	11	1.147	1.147	-0.001
10	15	1.167	1.167	0.000
10	20	1.155	1.156	-0.001
10	21	1.147	1.149	-0.001
10	24	1.144	1.144	0.001
30	1	1.160	1.160	0.000
30	5	1.168	1.169	-0.001
30	7	1.151	1.151	0.000
30	11	1.147	1.147	0.000
30	15	1.167	1.166	0.001
30	20	1.155	1.156	-0.001
30	21	1.147	1.149	-0.002
30	24	1.144	1.144	0.000
50	1	1.160	1.160	0.000
50	5	1.168	1.169	0.000
50	7	1.151	1.151	0.000
50	11	1.147	1.146	0.000
50	15	1.167	1.166	0.001
50	20	1.155	1.154	0.000
50	21	1.147	1.147	0.000
50	24	1.144	1.143	0.001
100	3	1.155	1.156	-0.001
100	8	1.159	1.160	-0.001
100	12	1.145	1.146	-0.001
100	13	1.156	1.157	-0.001
100	16	1.157	1.160	-0.003
100	17	1.158	1.160	-0.002
100	18	1.156	1.171	-0.015
100	19	1.159	1.160	-0.001
	Max	1.168	1.171	0.001
	Average	1.155	1.156	-0.001
	Min	1.144	1.143	-0.015
	Std Dev	0.008	0.008	0.003



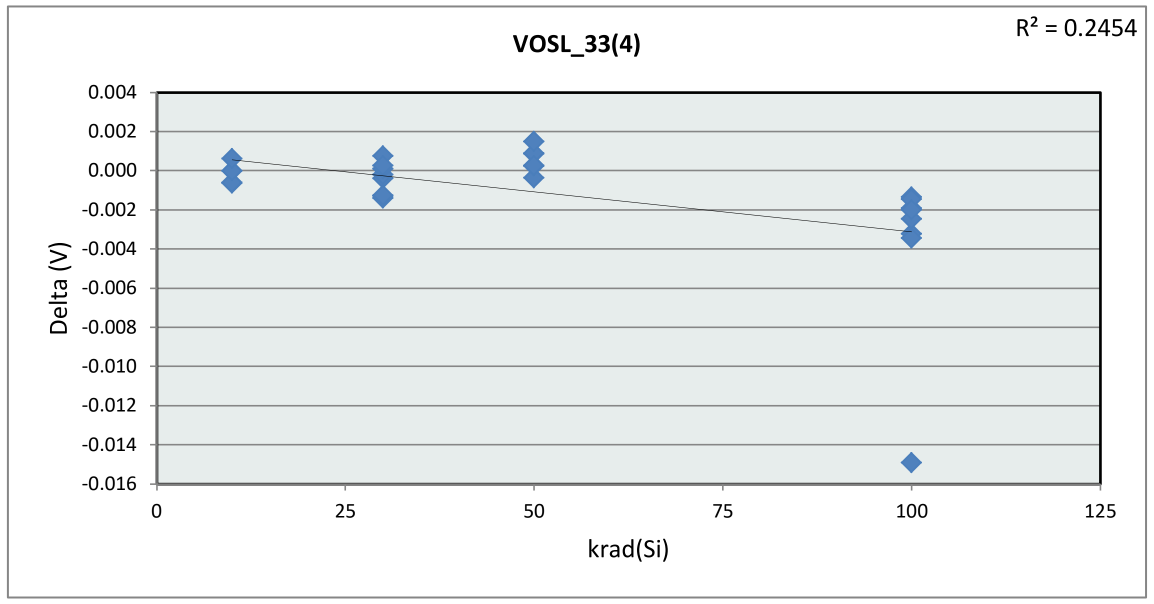
	VOSH_33(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	1.45	V
Min Limit	1	V

krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.144	1.144	1.143	1.146
Average	1.155	1.155	1.155	1.159
Max	1.169	1.169	1.169	1.171
UL	1.450	1.450	1.450	1.450

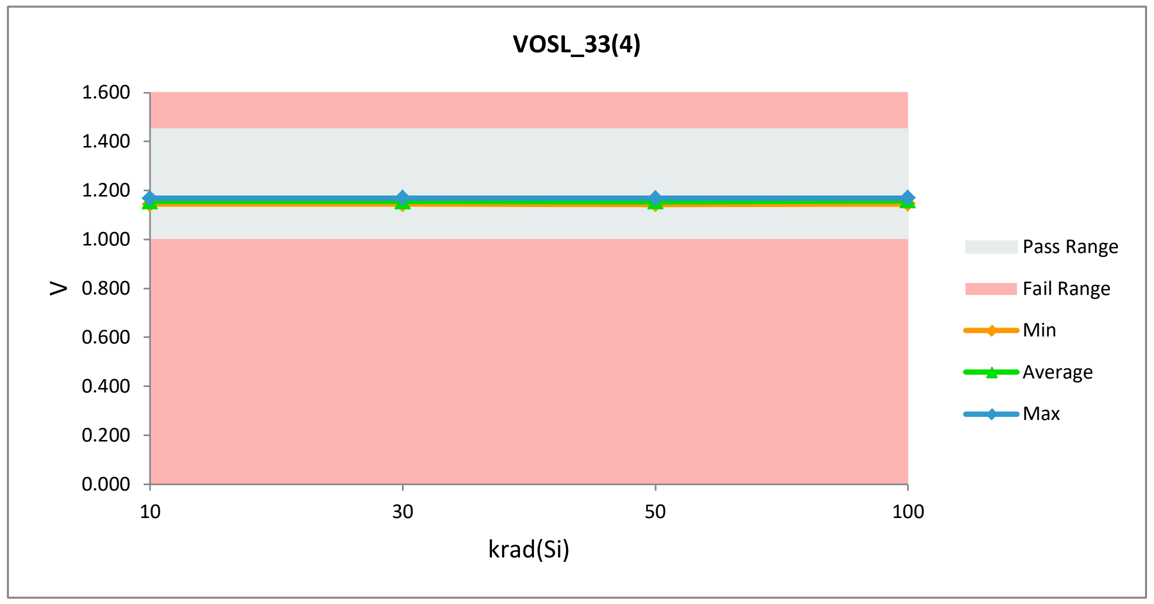


LDR Biased TID Report
SN55LVCP22A-SP

		VOSL_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.160	1.160	-0.001
10	5	1.168	1.168	-0.001
10	7	1.150	1.150	-0.001
10	11	1.146	1.146	0.000
10	15	1.166	1.166	0.000
10	20	1.155	1.155	-0.001
10	21	1.147	1.147	0.000
10	24	1.144	1.144	0.001
30	1	1.160	1.160	0.000
30	5	1.168	1.169	-0.001
30	7	1.150	1.150	0.000
30	11	1.146	1.146	0.000
30	15	1.166	1.165	0.001
30	20	1.155	1.156	-0.001
30	21	1.147	1.148	-0.001
30	24	1.144	1.144	0.000
50	1	1.160	1.159	0.000
50	5	1.168	1.168	0.000
50	7	1.150	1.150	0.000
50	11	1.146	1.145	0.001
50	15	1.166	1.164	0.001
50	20	1.155	1.154	0.001
50	21	1.147	1.146	0.000
50	24	1.144	1.143	0.001
100	3	1.154	1.156	-0.002
100	8	1.158	1.161	-0.003
100	12	1.144	1.145	-0.001
100	13	1.157	1.158	-0.001
100	16	1.157	1.160	-0.003
100	17	1.157	1.159	-0.002
100	18	1.154	1.169	-0.015
100	19	1.159	1.161	-0.002
	Max	1.168	1.169	0.001
	Average	1.154	1.155	-0.001
	Min	1.144	1.143	-0.015
	Std Dev	0.008	0.009	0.003

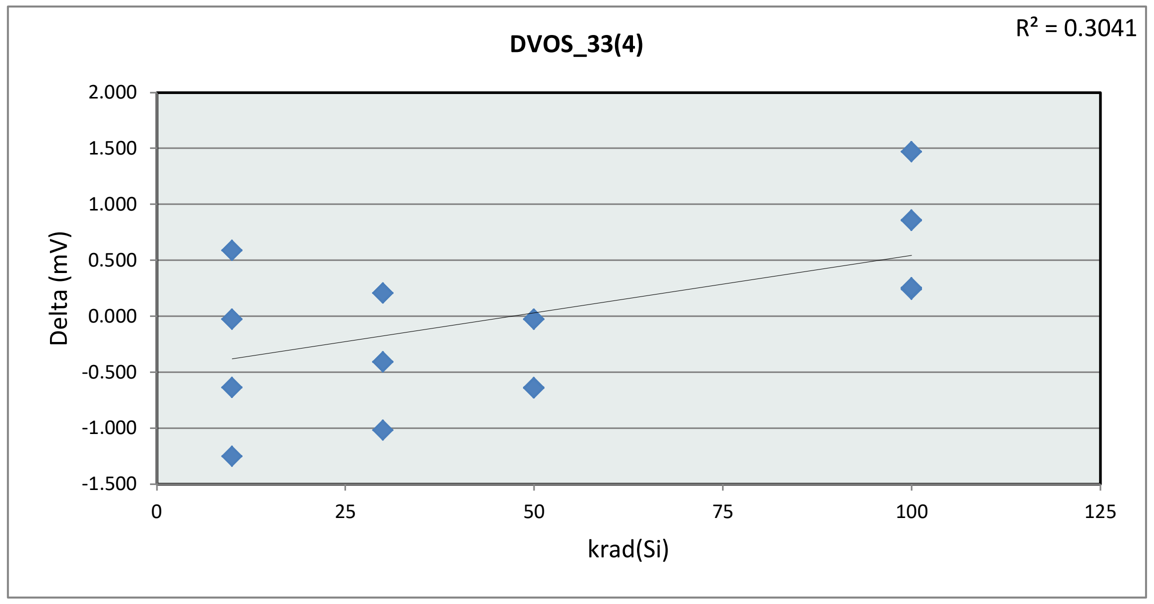


	VOSL_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.144	1.144	1.143	1.145
Average	1.155	1.155	1.154	1.159
Max	1.168	1.169	1.168	1.169
UL	1.450	1.450	1.450	1.450

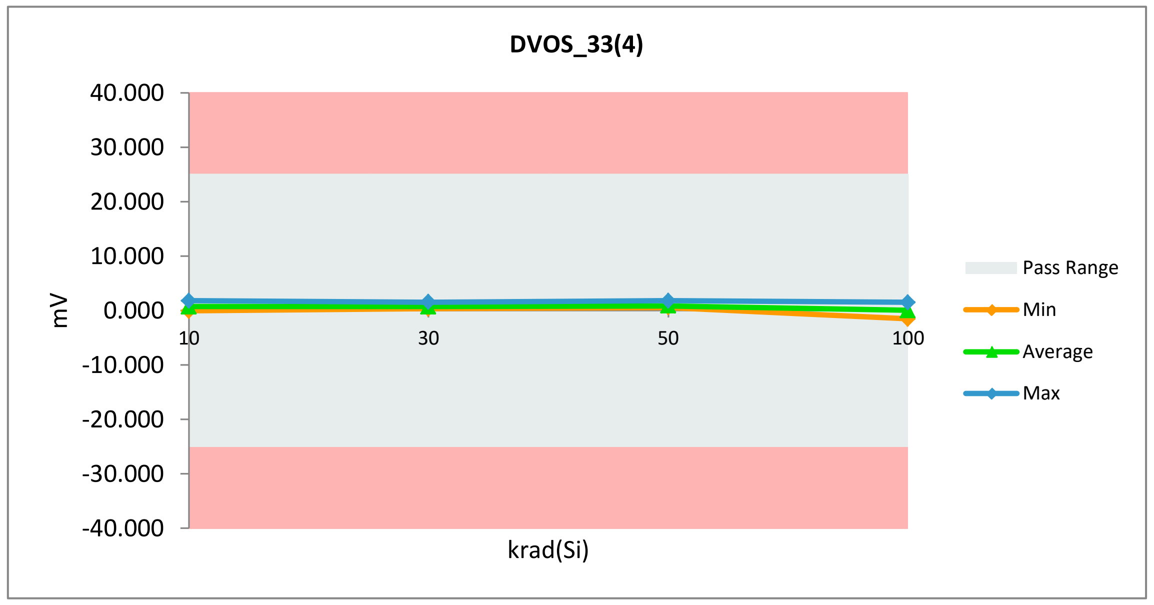


LDR Biased TID Report
SN55LVCP22A-SP

		DVOS_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	0.547	-0.041	0.587
10	5	0.546	0.573	-0.027
10	7	1.161	0.573	0.587
10	11	0.546	1.187	-0.641
10	15	1.161	1.187	-0.026
10	20	-0.067	0.574	-0.640
10	21	0.548	1.801	-1.254
10	24	-0.067	-0.040	-0.027
30	1	0.547	0.341	0.205
30	5	0.546	0.340	0.206
30	7	1.161	0.953	0.208
30	11	0.546	1.564	-1.018
30	15	1.161	0.955	0.206
30	20	-0.067	0.345	-0.411
30	21	0.548	0.957	-0.409
30	24	-0.067	0.342	-0.409
50	1	0.547	0.574	-0.027
50	5	0.546	0.574	-0.028
50	7	1.161	1.188	-0.027
50	11	0.546	1.187	-0.641
50	15	1.161	1.801	-0.641
50	20	-0.067	0.574	-0.641
50	21	0.548	0.575	-0.027
50	24	-0.067	0.574	-0.641
100	3	0.546	-0.311	0.858
100	8	1.161	-0.309	1.469
100	12	1.774	1.524	0.250
100	13	-0.681	-0.922	0.241
100	16	0.546	-0.309	0.855
100	17	1.161	0.914	0.247
100	18	1.774	1.521	0.253
100	19	-0.068	-1.534	1.466
	Max	1.774	1.801	1.469
	Average	0.604	0.601	0.003
	Min	-0.681	-1.534	-1.254
	Std Dev	0.570	0.758	0.634

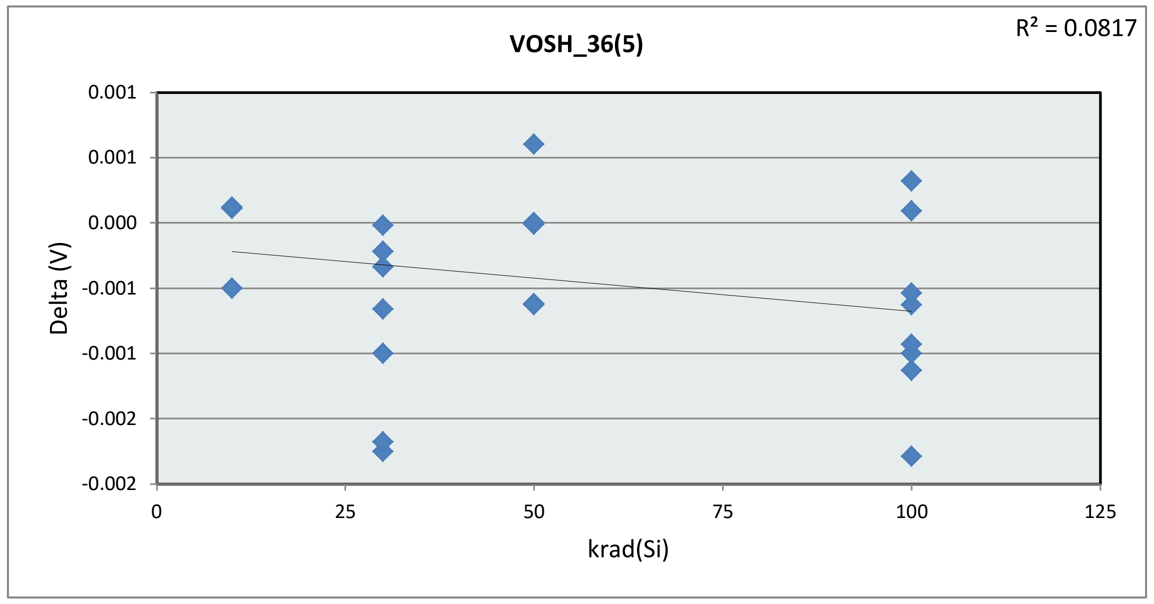


	DVOS_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.041	0.340	0.574	-1.534
Average	0.727	0.725	0.881	0.072
Max	1.801	1.564	1.801	1.524
UL	25.000	25.000	25.000	25.000

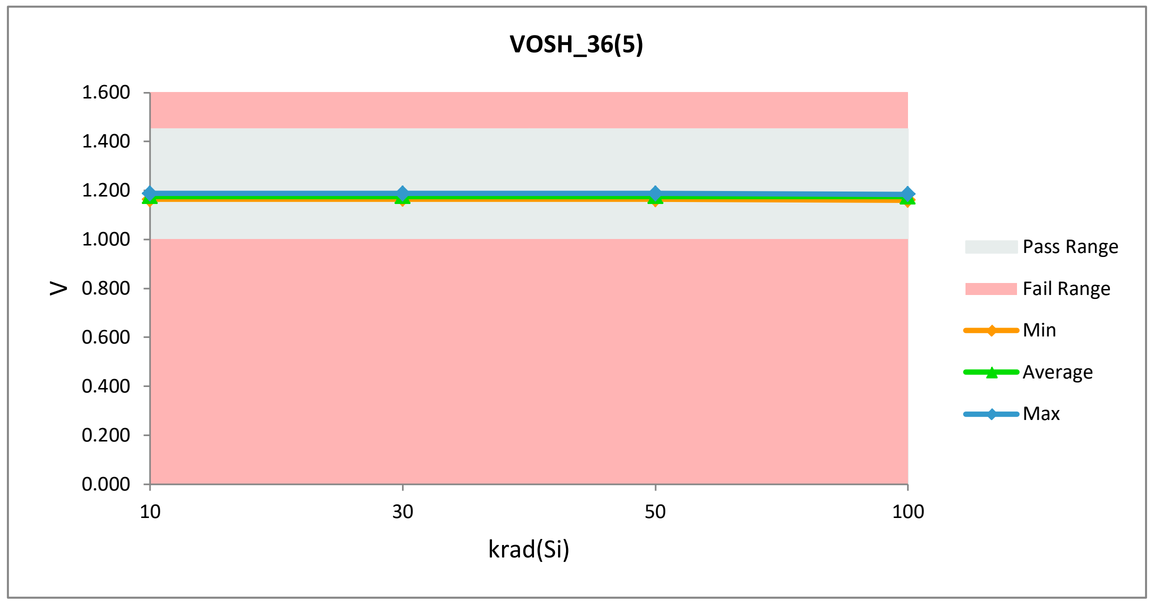


LDR Biased TID Report
SN55LVCP22A-SP

		VOSH_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.176	1.176	0.000
10	5	1.184	1.184	0.000
10	7	1.188	1.188	0.000
10	11	1.164	1.164	0.000
10	15	1.175	1.175	0.000
10	20	1.169	1.169	0.000
10	21	1.172	1.172	0.000
10	24	1.175	1.175	0.000
30	1	1.176	1.177	-0.001
30	5	1.184	1.184	0.000
30	7	1.188	1.188	0.000
30	11	1.164	1.165	-0.001
30	15	1.175	1.175	0.000
30	20	1.169	1.171	-0.002
30	21	1.172	1.174	-0.002
30	24	1.175	1.175	0.000
50	1	1.176	1.177	-0.001
50	5	1.184	1.185	-0.001
50	7	1.188	1.188	0.000
50	11	1.164	1.164	0.001
50	15	1.175	1.175	0.000
50	20	1.169	1.170	-0.001
50	21	1.172	1.172	0.000
50	24	1.175	1.175	0.000
100	3	1.158	1.160	-0.002
100	8	1.183	1.184	-0.001
100	12	1.176	1.177	-0.001
100	13	1.172	1.172	0.000
100	16	1.179	1.180	-0.001
100	17	1.178	1.179	-0.001
100	18	1.171	1.171	0.000
100	19	1.170	1.171	-0.001
	Max	1.188	1.188	0.001
	Average	1.175	1.175	0.000
	Min	1.158	1.160	-0.002
	Std Dev	0.007	0.007	0.001



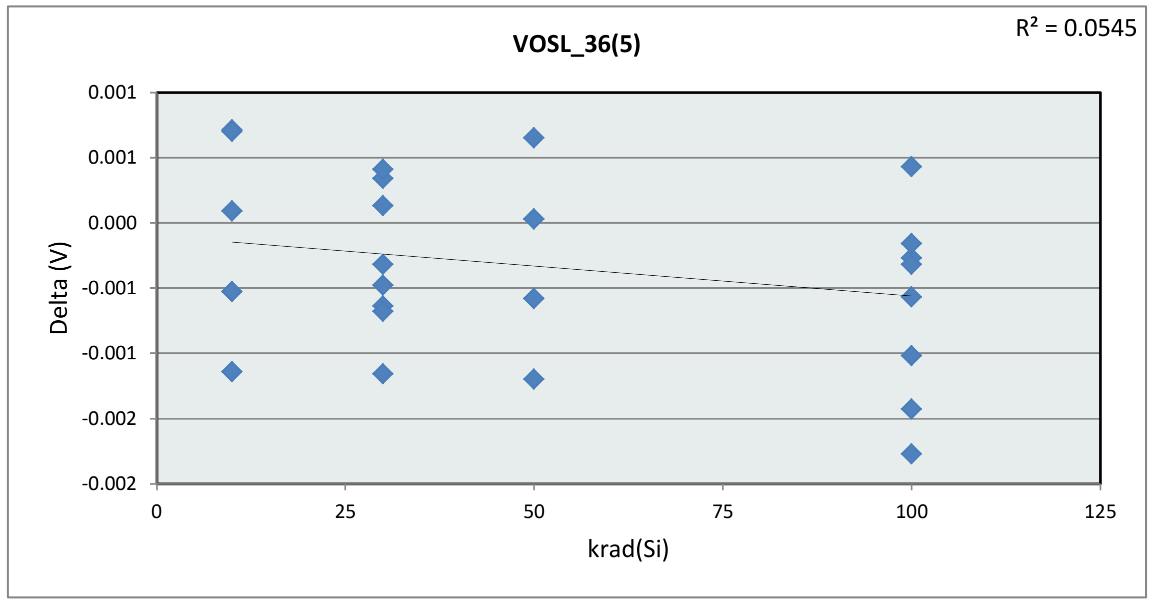
	VOSH_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.164	1.165	1.164	1.160
Average	1.175	1.176	1.176	1.174
Max	1.188	1.188	1.188	1.184
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
SN55LVCP22A-SP

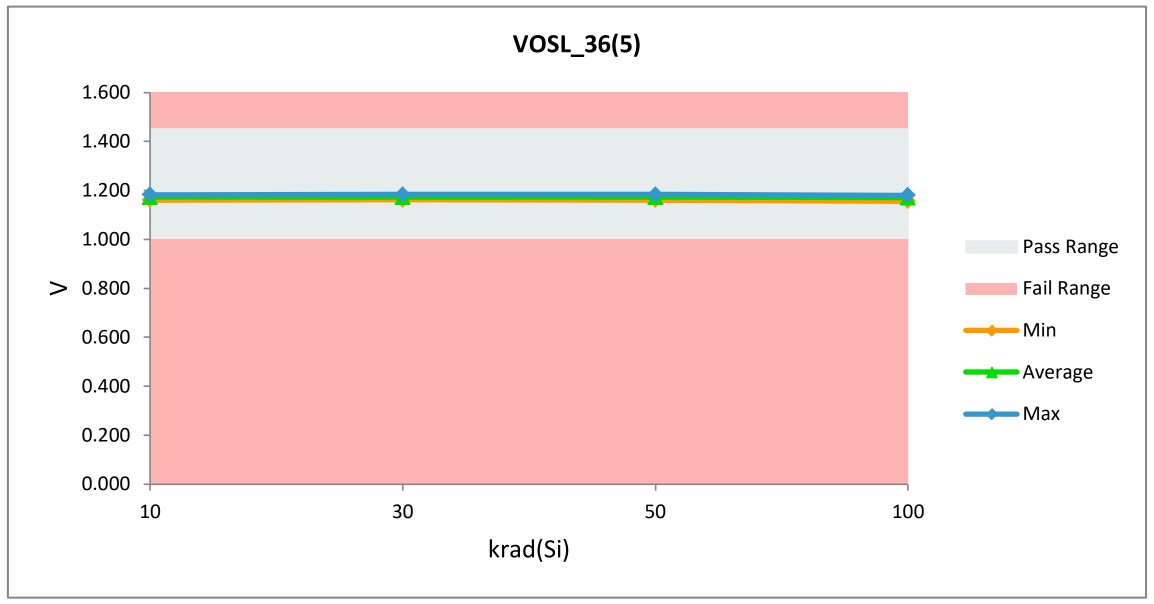
	VOSL_36(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.172	1.173	-0.001
10	5	1.180	1.181	-0.001
10	7	1.183	1.183	0.001
10	11	1.161	1.161	0.001
10	15	1.171	1.172	-0.001
10	20	1.167	1.167	0.000
10	21	1.169	1.169	0.000
10	24	1.171	1.172	-0.001
30	1	1.172	1.173	-0.001
30	5	1.180	1.180	0.000
30	7	1.183	1.183	0.000
30	11	1.161	1.162	-0.001
30	15	1.171	1.171	0.000
30	20	1.167	1.168	-0.001
30	21	1.169	1.169	0.000
30	24	1.171	1.171	0.000
50	1	1.172	1.172	0.000
50	5	1.180	1.181	-0.001
50	7	1.183	1.183	0.001
50	11	1.161	1.161	0.001
50	15	1.171	1.172	-0.001
50	20	1.167	1.167	-0.001
50	21	1.169	1.169	0.000
50	24	1.171	1.171	0.000
100	3	1.155	1.156	-0.001
100	8	1.180	1.180	0.000
100	12	1.173	1.174	-0.001
100	13	1.169	1.169	0.000
100	16	1.175	1.176	-0.001
100	17	1.175	1.175	0.000
100	18	1.167	1.167	0.000
100	19	1.166	1.168	-0.002
	Max	1.183	1.183	0.001
	Average	1.171	1.172	0.000
	Min	1.155	1.156	-0.002
	Std Dev	0.007	0.007	0.001



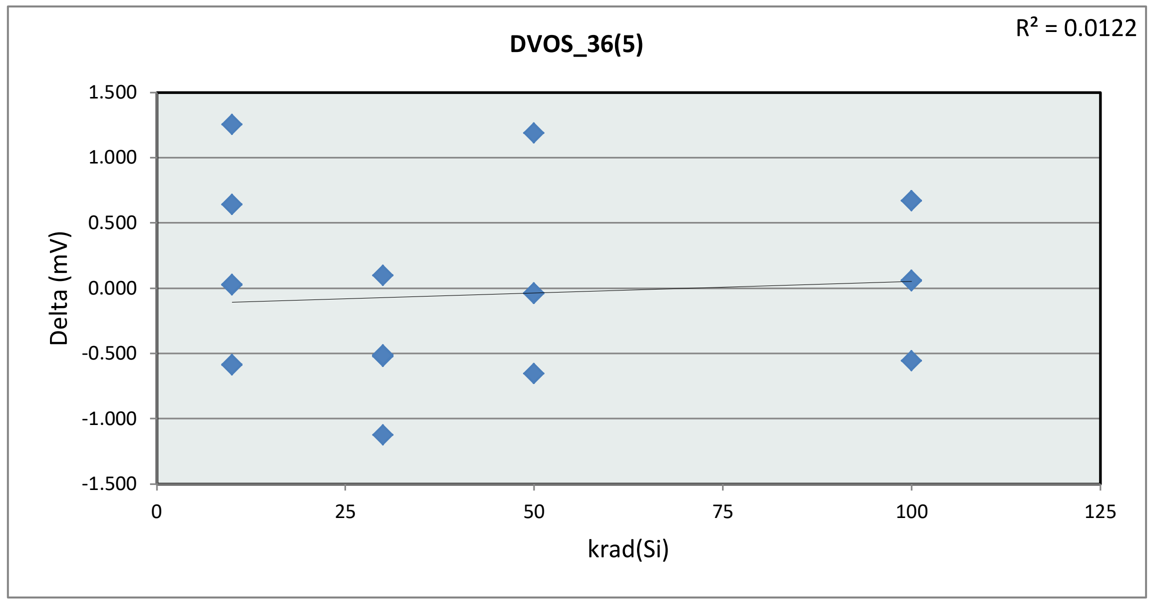
	VOSL_36(5)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	1.45	V
Min Limit	1	V

krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.161	1.162	1.161	1.156
Average	1.172	1.172	1.172	1.171
Max	1.183	1.183	1.183	1.180
UL	1.450	1.450	1.450	1.450

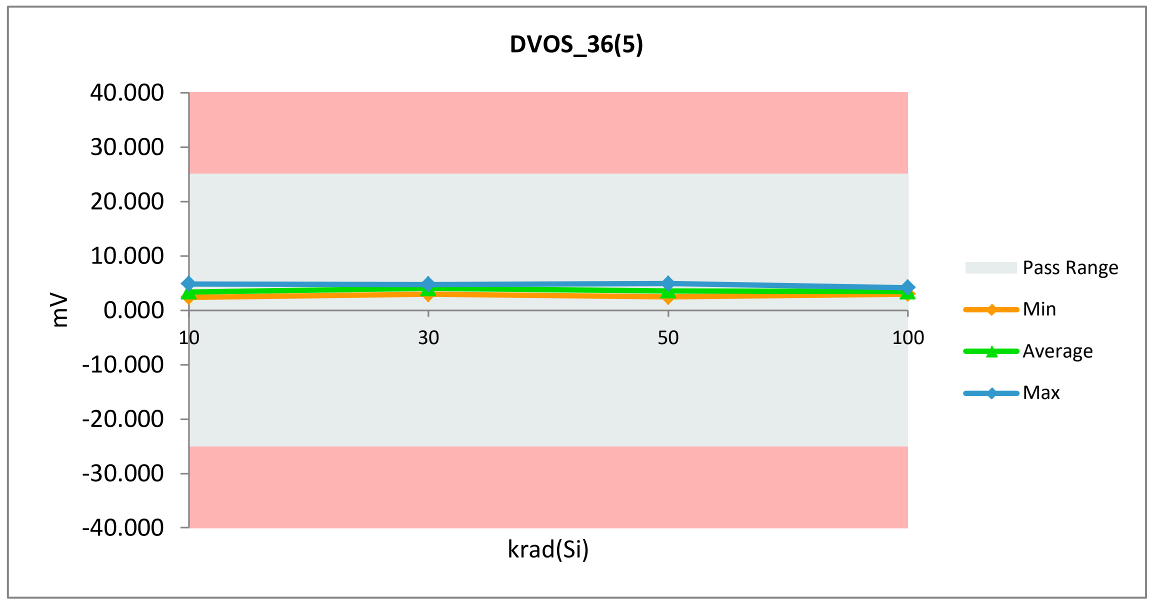


LDR Biased TID Report
SN55LVCP22A-SP

		DVOS_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	3.640	3.614	0.025
10	5	3.639	2.386	1.253
10	7	4.253	4.840	-0.587
10	11	3.027	3.615	-0.589
10	15	4.254	3.616	0.639
10	20	2.414	2.389	0.025
10	21	3.640	3.615	0.025
10	24	3.641	3.002	0.638
30	1	3.640	4.154	-0.514
30	5	3.639	3.541	0.098
30	7	4.253	4.763	-0.510
30	11	3.027	3.545	-0.518
30	15	4.254	4.157	0.097
30	20	2.414	2.936	-0.522
30	21	3.640	4.766	-1.126
30	24	3.641	4.157	-0.516
50	1	3.640	4.294	-0.654
50	5	3.639	3.680	-0.042
50	7	4.253	4.908	-0.655
50	11	3.027	3.067	-0.040
50	15	4.254	3.067	1.188
50	20	2.414	2.453	-0.040
50	21	3.640	3.680	-0.040
50	24	3.641	3.680	-0.040
100	3	3.639	3.582	0.057
100	8	3.640	3.583	0.057
100	12	3.026	2.972	0.054
100	13	3.641	2.973	0.668
100	16	3.641	3.584	0.057
100	17	3.026	3.582	-0.556
100	18	4.254	4.193	0.061
100	19	3.640	2.971	0.669
	Max	4.254	4.908	1.253
	Average	3.563	3.605	-0.042
	Min	2.414	2.386	-1.126
	Std Dev	0.534	0.685	0.543

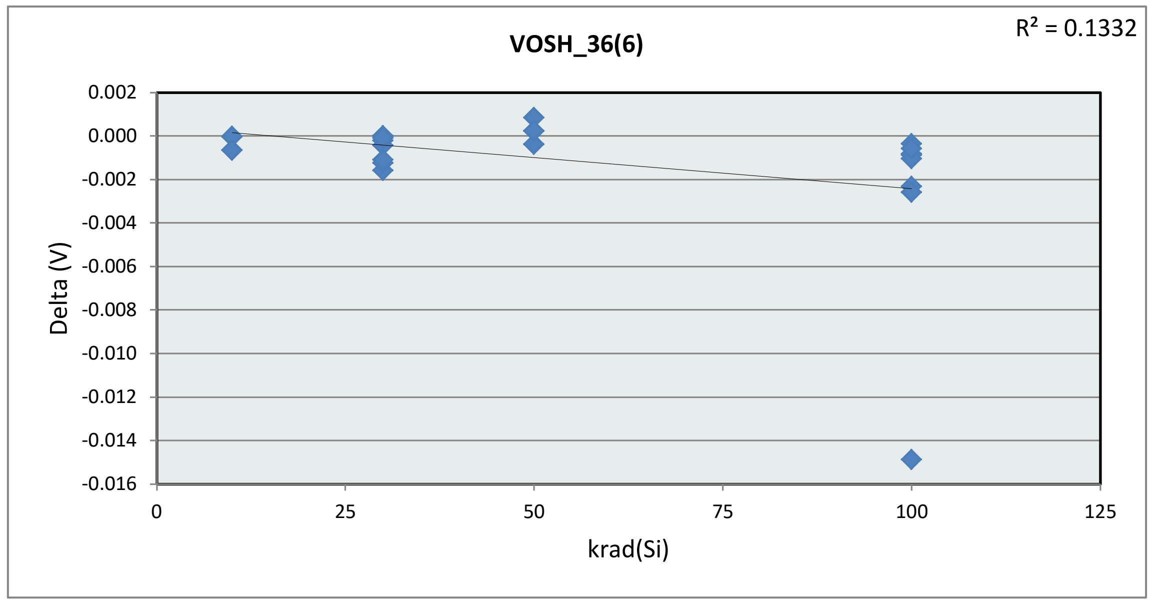


	DVOS_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.386	2.936	2.453	2.971
Average	3.385	4.002	3.604	3.430
Max	4.840	4.766	4.908	4.193
UL	25.000	25.000	25.000	25.000

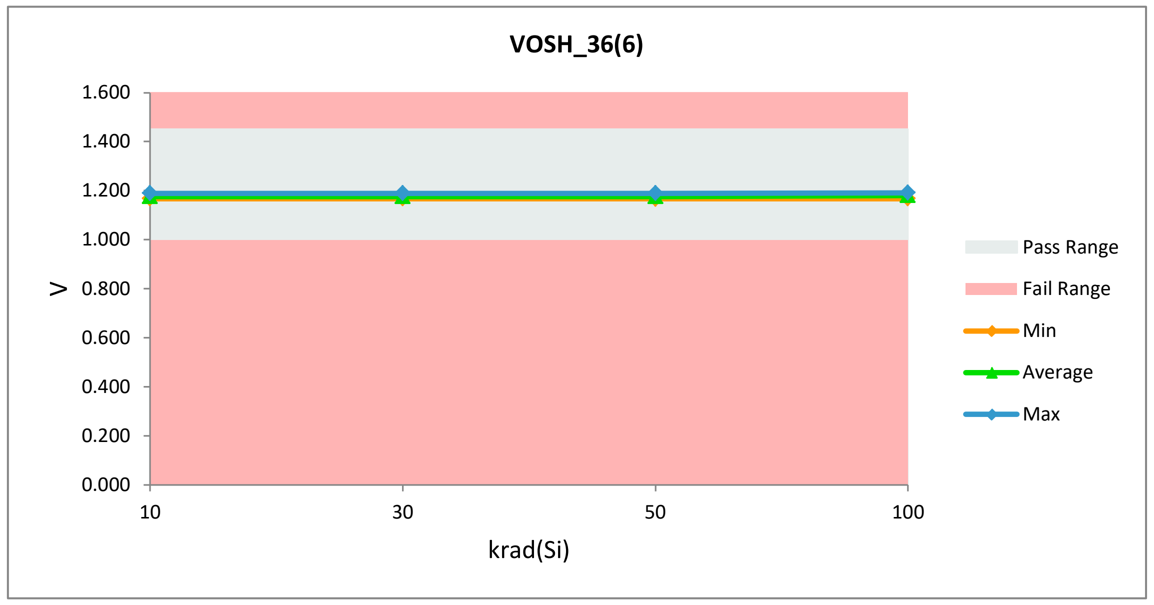


LDR Biased TID Report
SN55LVCP22A-SP

		VOSH_36(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.180	1.181	-0.001
10	5	1.188	1.188	-0.001
10	7	1.170	1.170	0.000
10	11	1.169	1.169	0.000
10	15	1.189	1.190	-0.001
10	20	1.179	1.179	0.000
10	21	1.167	1.168	-0.001
10	24	1.167	1.168	-0.001
30	1	1.180	1.182	-0.002
30	5	1.188	1.188	0.000
30	7	1.170	1.170	0.000
30	11	1.169	1.170	-0.001
30	15	1.189	1.189	0.000
30	20	1.179	1.179	0.000
30	21	1.167	1.167	0.000
30	24	1.167	1.168	-0.001
50	1	1.180	1.180	0.000
50	5	1.188	1.188	0.000
50	7	1.170	1.170	0.000
50	11	1.169	1.168	0.001
50	15	1.189	1.189	0.000
50	20	1.179	1.179	0.000
50	21	1.167	1.166	0.001
50	24	1.167	1.167	0.000
100	3	1.176	1.177	-0.001
100	8	1.182	1.182	0.000
100	12	1.166	1.168	-0.002
100	13	1.179	1.180	-0.001
100	16	1.180	1.183	-0.003
100	17	1.178	1.179	-0.001
100	18	1.176	1.191	-0.015
100	19	1.180	1.181	-0.001
	Max	1.189	1.191	0.001
	Average	1.176	1.177	-0.001
	Min	1.166	1.166	-0.015
	Std Dev	0.008	0.008	0.003



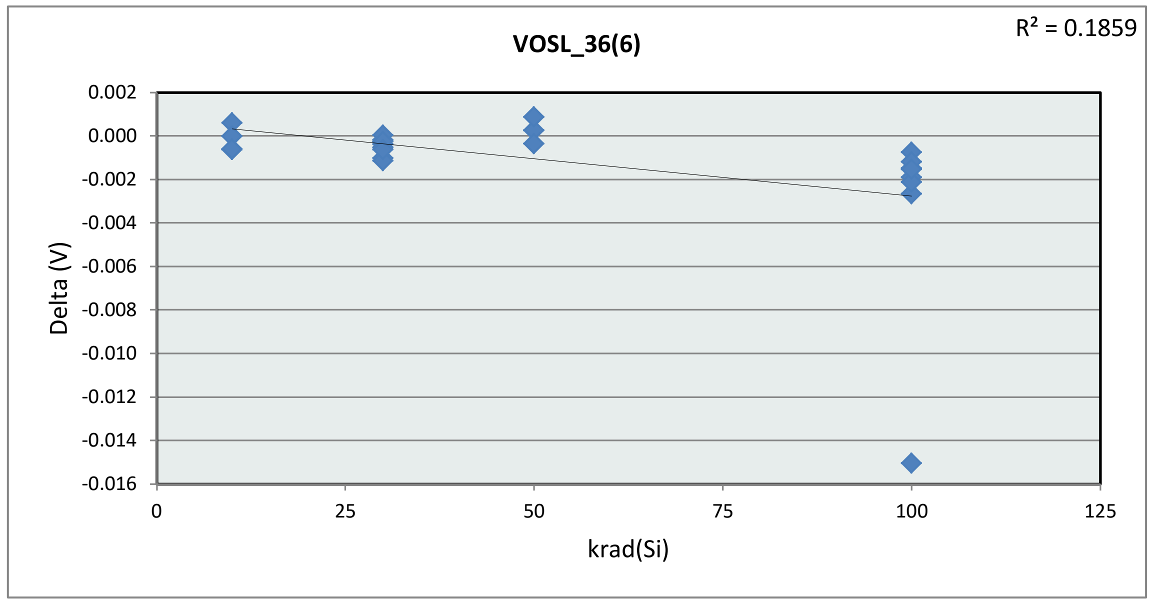
	VOSH_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.168	1.167	1.166	1.168
Average	1.176	1.177	1.176	1.180
Max	1.190	1.189	1.189	1.191
UL	1.450	1.450	1.450	1.450



LDR Biased TID Report
SN55LVCP22A-SP

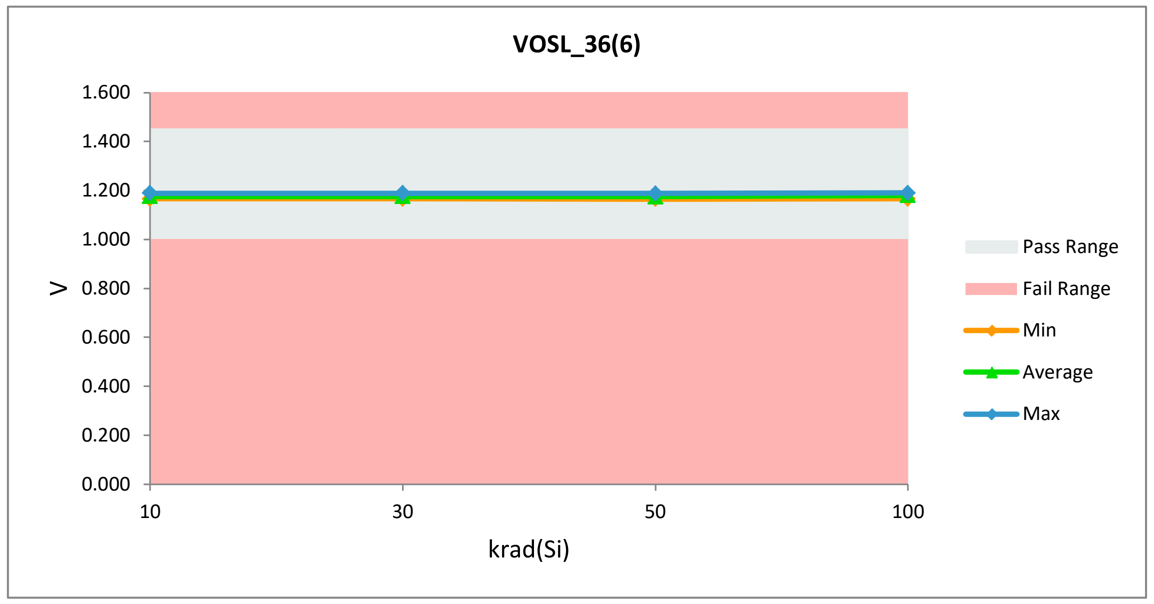
	VOSL_36(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	1.180	1.181	-0.001
10	5	1.187	1.187	-0.001
10	7	1.169	1.168	0.001
10	11	1.167	1.167	0.000
10	15	1.188	1.188	-0.001
10	20	1.178	1.178	0.000
10	21	1.166	1.166	-0.001
10	24	1.166	1.167	-0.001
30	1	1.180	1.181	-0.001
30	5	1.187	1.187	0.000
30	7	1.169	1.169	0.000
30	11	1.167	1.168	-0.001
30	15	1.188	1.189	-0.001
30	20	1.178	1.178	0.000
30	21	1.166	1.166	0.000
30	24	1.166	1.167	-0.001
50	1	1.180	1.180	0.000
50	5	1.187	1.187	0.000
50	7	1.169	1.168	0.001
50	11	1.167	1.166	0.001
50	15	1.188	1.188	0.000
50	20	1.178	1.178	0.000
50	21	1.166	1.165	0.001
50	24	1.166	1.167	0.000
100	3	1.174	1.177	-0.003
100	8	1.181	1.183	-0.002
100	12	1.165	1.166	-0.001
100	13	1.179	1.180	-0.001
100	16	1.180	1.182	-0.002
100	17	1.177	1.178	-0.001
100	18	1.175	1.190	-0.015
100	19	1.180	1.182	-0.002
	Max	1.188	1.190	0.001
	Average	1.175	1.176	-0.001
	Min	1.165	1.165	-0.015
	Std Dev	0.008	0.009	0.003



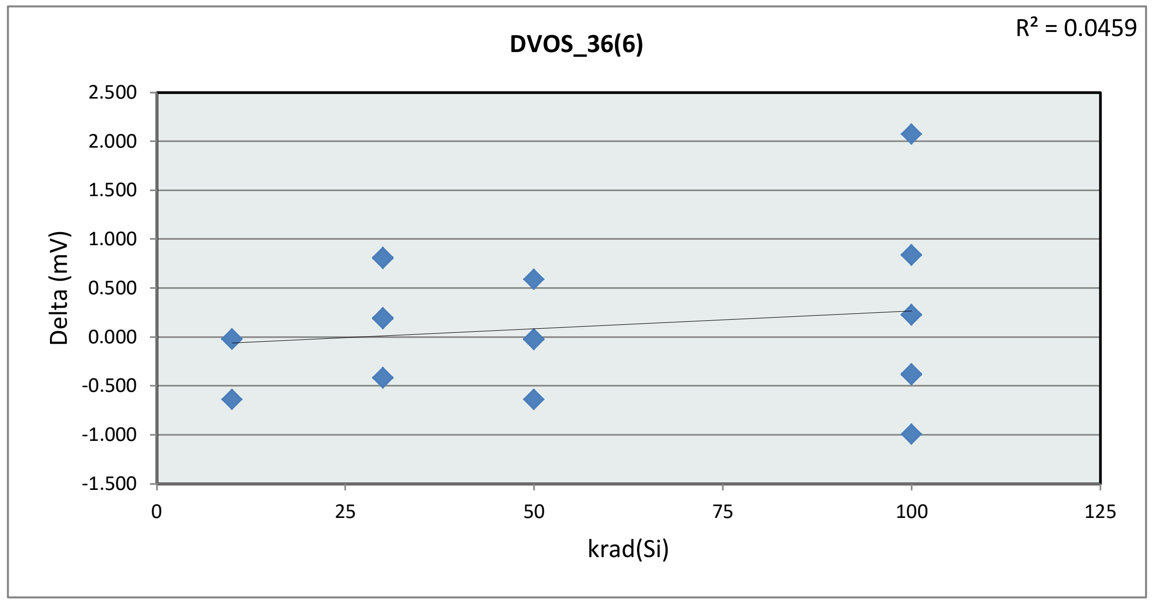
	VOSL_36(6)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	1.45	V
Min Limit	1	V

krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.166	1.166	1.165	1.166
Average	1.175	1.176	1.175	1.180
Max	1.188	1.189	1.188	1.190
UL	1.450	1.450	1.450	1.450

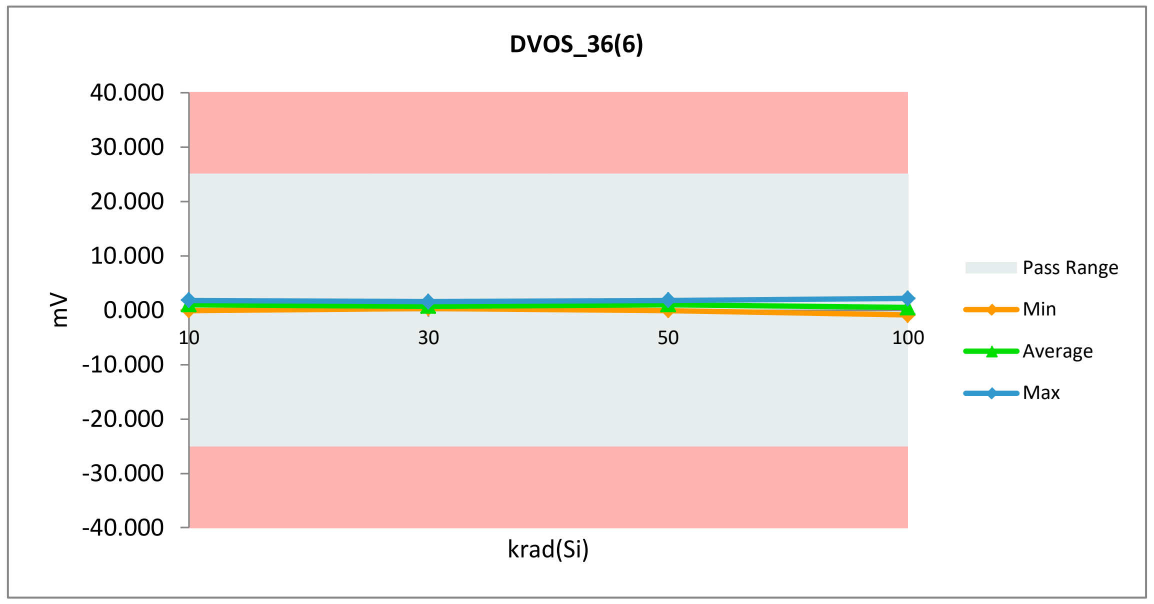


LDR Biased TID Report
SN55LVCP22A-SP

		DVOS_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	LDR Pre Test	LDR Post Test	Delta
10	1	-0.063	-0.038	-0.025
10	5	1.163	1.189	-0.026
10	7	1.165	1.804	-0.638
10	11	1.779	1.804	-0.024
10	15	1.166	1.191	-0.024
10	20	0.554	0.577	-0.024
10	21	1.166	1.190	-0.024
10	24	0.552	0.577	-0.024
30	1	-0.063	0.361	-0.424
30	5	1.163	0.353	0.810
30	7	1.165	1.583	-0.418
30	11	1.779	1.585	0.194
30	15	1.166	0.367	0.800
30	20	0.554	0.370	0.184
30	21	1.166	0.977	0.190
30	24	0.552	0.365	0.187
50	1	-0.063	-0.037	-0.026
50	5	1.163	1.189	-0.026
50	7	1.165	1.804	-0.639
50	11	1.779	1.804	-0.025
50	15	1.166	1.191	-0.025
50	20	0.554	1.192	-0.638
50	21	1.166	1.191	-0.025
50	24	0.552	-0.036	0.589
100	3	1.778	-0.293	2.071
100	8	0.552	-0.284	0.836
100	12	1.165	2.158	-0.993
100	13	-0.062	-0.285	0.223
100	16	0.552	0.941	-0.388
100	17	1.165	0.935	0.230
100	18	1.166	1.541	-0.375
100	19	-0.063	-0.903	0.840
	Max	1.779	2.158	2.071
	Average	0.897	0.824	0.073
	Min	-0.063	-0.903	-0.993
	Std Dev	0.561	0.770	0.576



	DVOS_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.038	0.353	-0.037	-0.903
Average	1.037	0.745	1.037	0.476
Max	1.804	1.585	1.804	2.158
UL	25.000	25.000	25.000	25.000

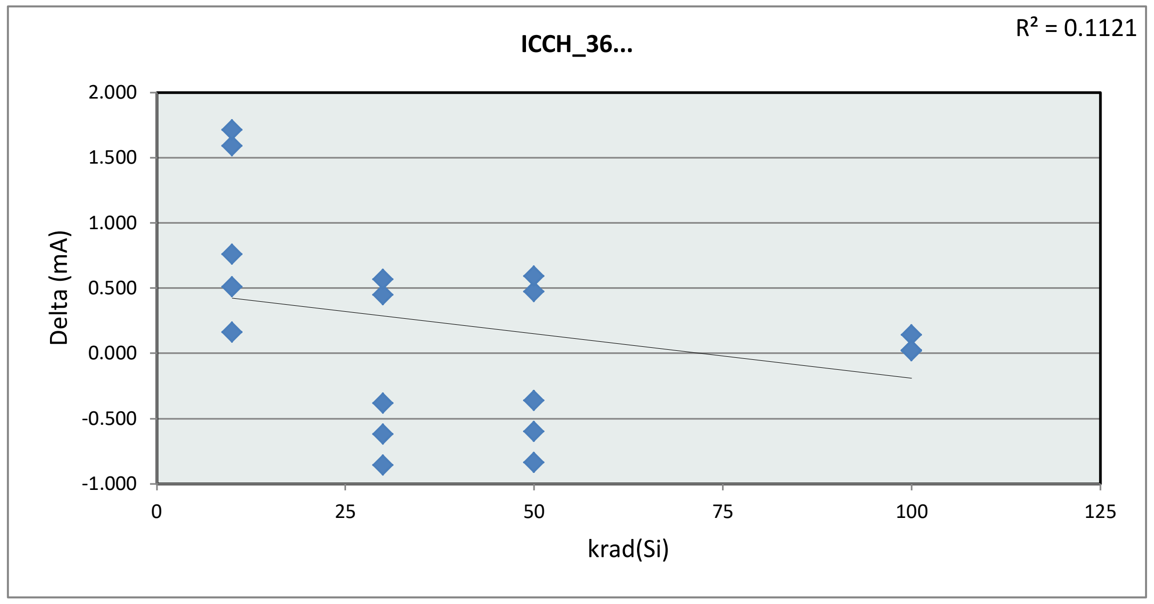


Delta Threshold 10.00%

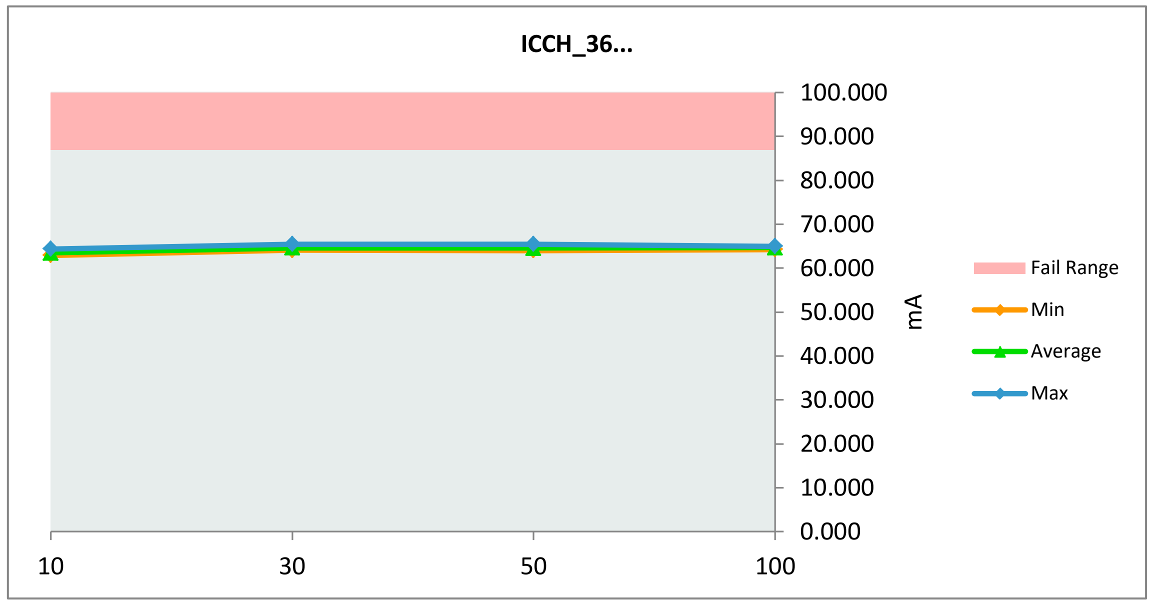
LDR UnBiased TID Report
SN55LVCP22A-SP

LDR UnBiased TID Report
SN55LVCP22A-SP

		ICCH_36...		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	87	87	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	64.984	63.397	1.587
10	7	64.627	62.917	1.710
10	8	64.865	64.357	0.508
10	9	63.915	63.157	0.758
10	10	63.796	63.637	0.159
30	6	64.984	64.535	0.449
30	7	64.627	64.059	0.568
30	8	64.865	65.485	-0.620
30	9	63.915	64.297	-0.382
30	10	63.796	64.653	-0.857
50	6	64.984	64.513	0.471
50	7	64.627	64.038	0.589
50	8	64.865	65.464	-0.599
50	9	63.915	64.276	-0.361
50	10	63.796	64.632	-0.836
100	B011	64.509	64.489	0.020
100	B012	64.271	64.251	0.020
100	B013	64.865	64.846	0.019
100	B014	65.103	64.964	0.139
100	B015	64.984	64.964	0.020
	Max	65.103	65.485	1.710
	Average	64.515	64.347	0.168
	Min	63.796	62.917	-0.857
	Std Dev	0.484	0.683	0.700



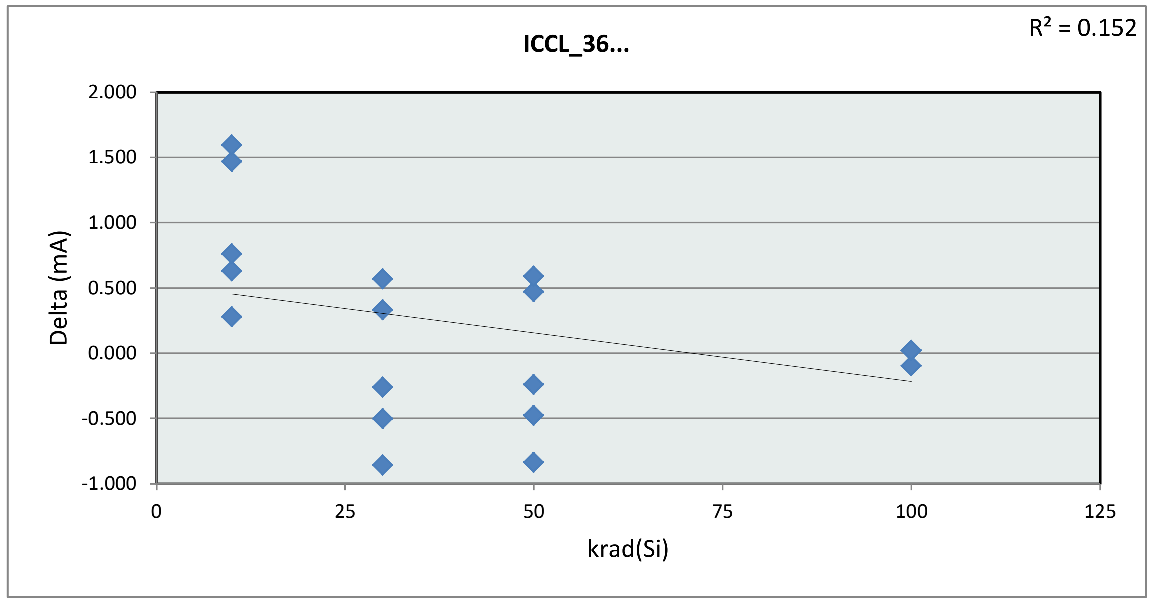
	ICCH_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	62.917	64.059	64.038	64.251
Average	63.493	64.606	64.585	64.703
Max	64.357	65.485	65.464	64.964
UL	87.000	87.000	87.000	87.000



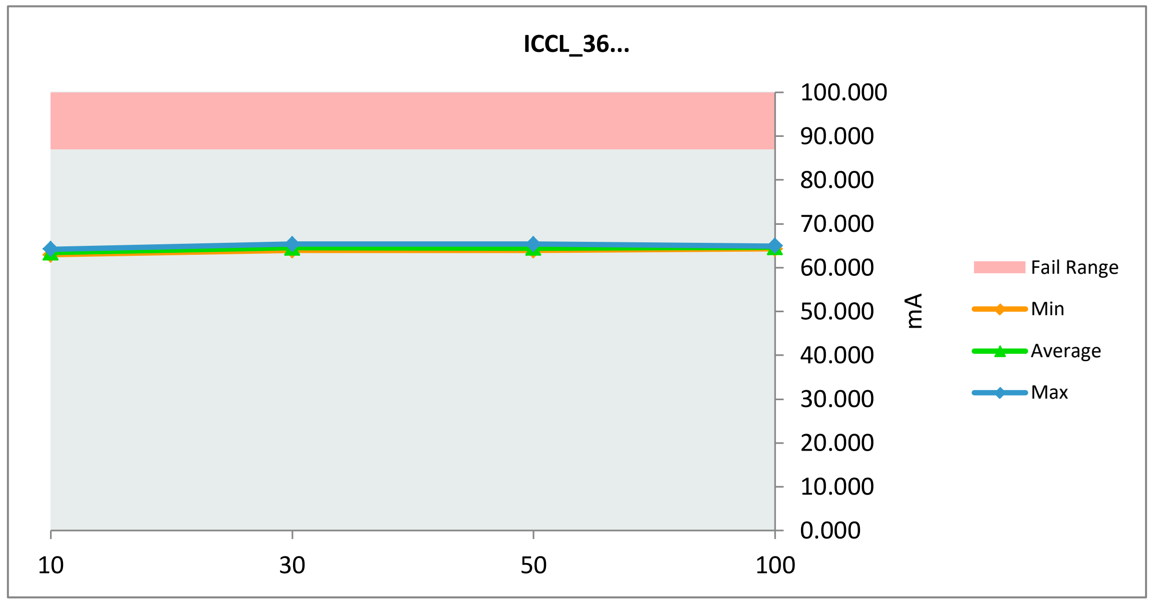
LDR UnBiased TID Report
SN55LVCP22A-SP

	ICCL_36...	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	87	87
Min Limit		

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	64.865	63.397	1.468
10	7	64.509	62.917	1.592
10	8	64.865	64.237	0.628
10	9	63.915	63.157	0.758
10	10	63.796	63.517	0.279
30	6	64.865	64.535	0.330
30	7	64.509	63.940	0.569
30	8	64.865	65.367	-0.502
30	9	63.915	64.178	-0.263
30	10	63.796	64.653	-0.857
50	6	64.865	64.395	0.470
50	7	64.509	63.919	0.590
50	8	64.865	65.345	-0.480
50	9	63.915	64.157	-0.242
50	10	63.796	64.632	-0.836
100	B011	64.390	64.370	0.020
100	B012	64.152	64.251	-0.099
100	B013	64.865	64.846	0.019
100	B014	64.984	64.964	0.020
100	B015	64.865	64.846	0.019
	Max	64.984	65.367	1.592
	Average	64.455	64.281	0.174
	Min	63.796	62.917	-0.857
	Std Dev	0.453	0.670	0.656

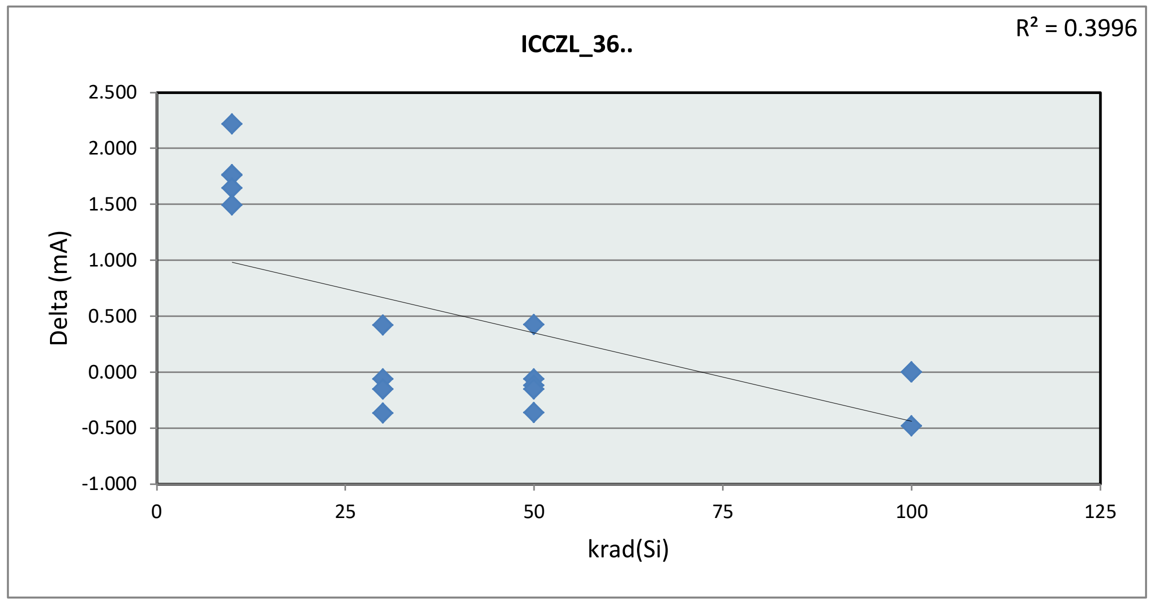


	ICCL_36...			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	87	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	62.917	63.940	63.919	64.251
Average	63.445	64.535	64.490	64.655
Max	64.237	65.367	65.345	64.964
UL	87.000	87.000	87.000	87.000

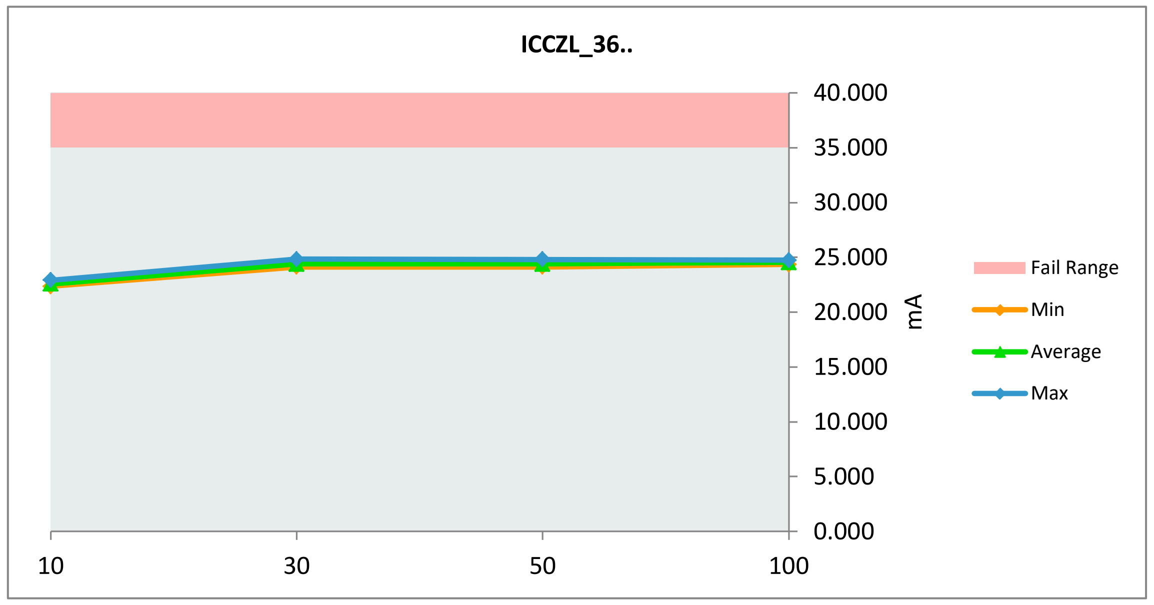


LDR UnBiased TID Report
SN55LVCP22A-SP

		ICCZL_36..		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	35	35	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	24.258	22.495	1.763
10	7	24.560	22.343	2.217
10	8	24.681	22.920	1.761
10	9	24.107	22.465	1.642
10	10	24.077	22.586	1.491
30	6	24.258	24.322	-0.064
30	7	24.560	24.141	0.419
30	8	24.681	24.835	-0.154
30	9	24.107	24.261	-0.154
30	10	24.077	24.442	-0.365
50	6	24.258	24.318	-0.060
50	7	24.560	24.137	0.423
50	8	24.681	24.801	-0.120
50	9	24.107	24.258	-0.151
50	10	24.077	24.439	-0.362
100	B011	24.439	24.439	0.000
100	B012	24.349	24.348	0.001
100	B013	24.560	24.559	0.001
100	B014	24.681	24.680	0.001
100	B015	24.258	24.740	-0.482
	Max	24.681	24.835	2.217
	Average	24.367	23.976	0.390
	Min	24.077	22.343	-0.482
	Std Dev	0.235	0.867	0.857



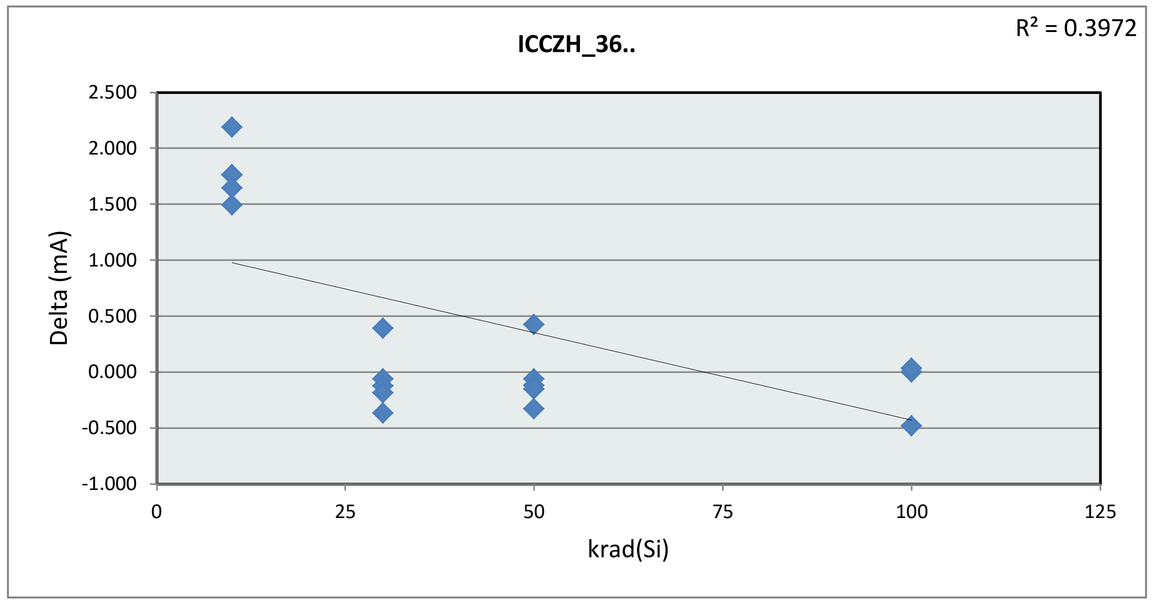
	ICCZL_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	22.343	24.141	24.137	24.348
Average	22.562	24.400	24.391	24.553
Max	22.920	24.835	24.801	24.740
UL	35.000	35.000	35.000	35.000



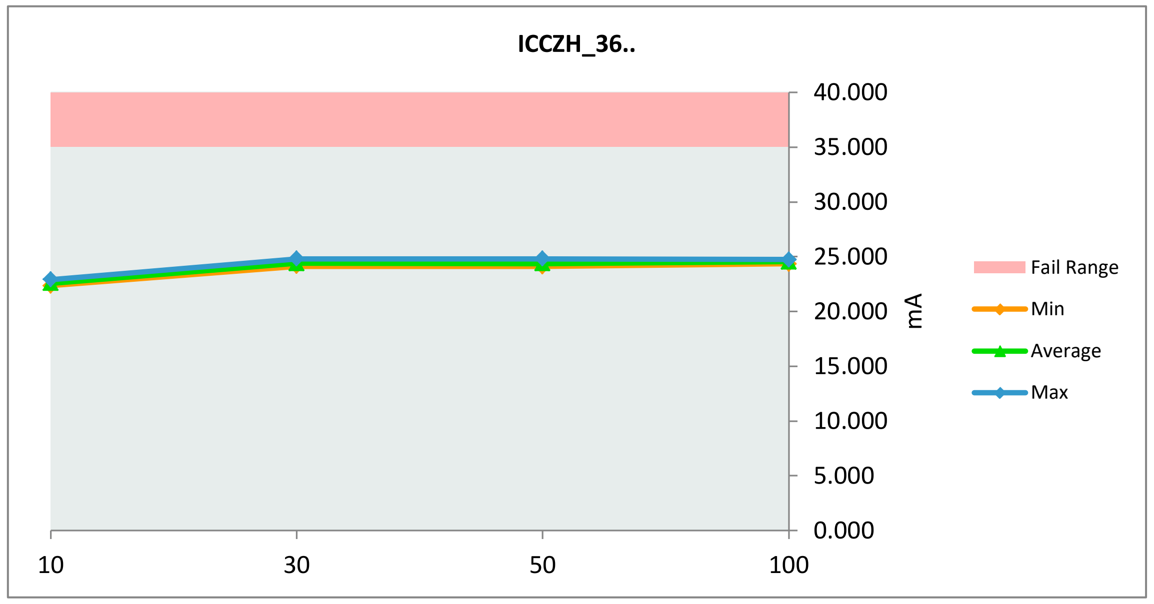
LDR UnBiased TID Report
SN55LVCP22A-SP

	ICCZH_36..	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	35	35
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	24.258	22.495	1.763
10	7	24.530	22.343	2.187
10	8	24.681	22.920	1.761
10	9	24.107	22.465	1.642
10	10	24.077	22.586	1.491
30	6	24.258	24.322	-0.064
30	7	24.530	24.141	0.389
30	8	24.681	24.804	-0.123
30	9	24.107	24.291	-0.184
30	10	24.077	24.442	-0.365
50	6	24.258	24.318	-0.060
50	7	24.530	24.107	0.423
50	8	24.681	24.801	-0.120
50	9	24.107	24.258	-0.151
50	10	24.077	24.408	-0.331
100	B011	24.439	24.439	0.000
100	B012	24.349	24.348	0.001
100	B013	24.560	24.559	0.001
100	B014	24.711	24.680	0.031
100	B015	24.258	24.740	-0.482
	Max	24.711	24.804	2.187
	Average	24.364	23.973	0.390
	Min	24.077	22.343	-0.482
	Std Dev	0.234	0.864	0.851

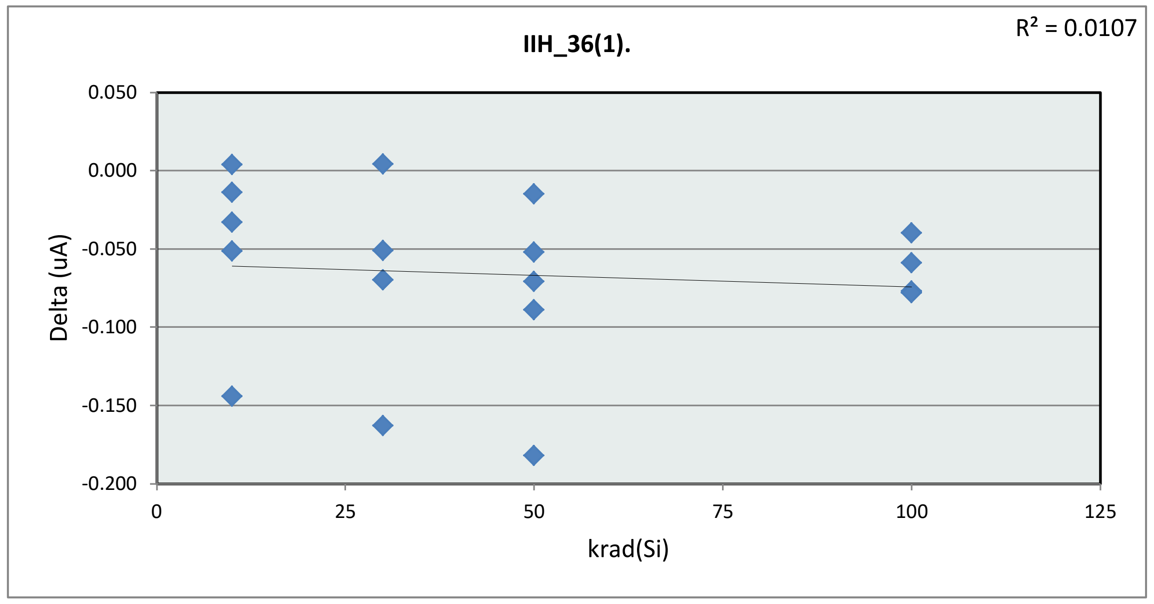


	ICCZH_36..			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	35	mA		
Min Limit		mA		
krad(Si)	10	30	50	100
LL				
Min	22.343	24.141	24.107	24.348
Average	22.562	24.400	24.378	24.553
Max	22.920	24.804	24.801	24.740
UL	35.000	35.000	35.000	35.000

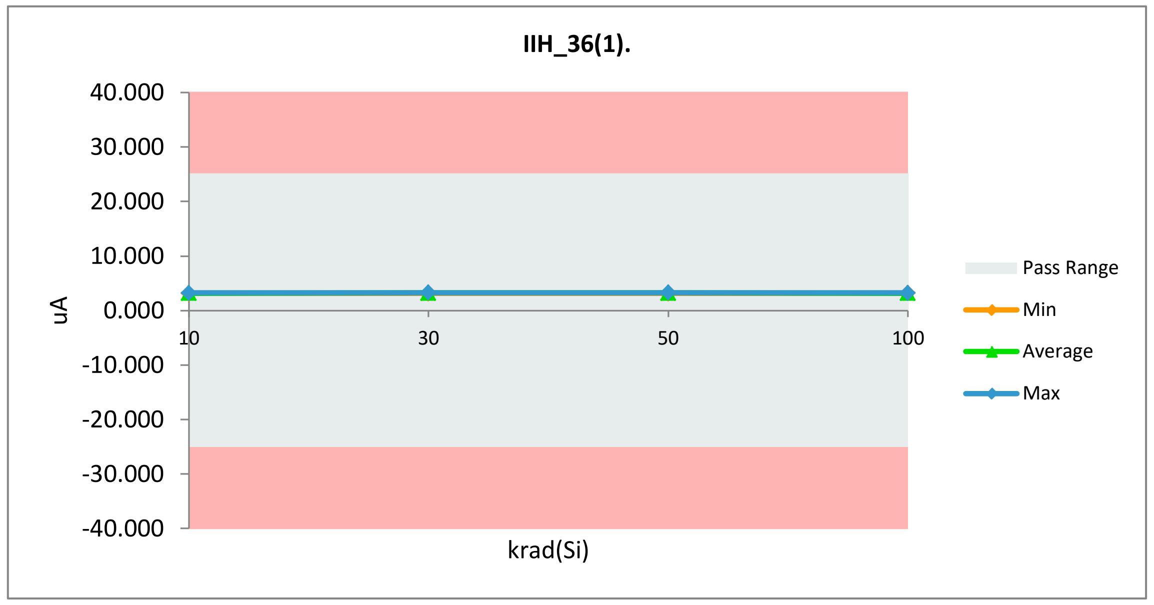


LDR UnBiased TID Report
SN55LVCP22A-SP

		IIH_36(1).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		25	25	
Min Limit		-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	3.141	3.192	-0.051
10	7	3.104	3.248	-0.144
10	8	3.104	3.118	-0.014
10	9	3.215	3.211	0.004
10	10	3.178	3.211	-0.033
30	6	3.141	3.211	-0.070
30	7	3.104	3.267	-0.163
30	8	3.104	3.155	-0.051
30	9	3.215	3.211	0.004
30	10	3.178	3.248	-0.070
50	6	3.141	3.230	-0.089
50	7	3.104	3.286	-0.182
50	8	3.104	3.156	-0.052
50	9	3.215	3.230	-0.015
50	10	3.178	3.249	-0.071
100	B011	3.141	3.218	-0.077
100	B012	3.122	3.200	-0.078
100	B013	3.122	3.162	-0.040
100	B014	3.122	3.200	-0.078
100	B015	3.141	3.200	-0.059
	Max	3.215	3.286	0.004
	Average	3.144	3.210	-0.066
	Min	3.104	3.118	-0.182
	Std Dev	0.040	0.041	0.050



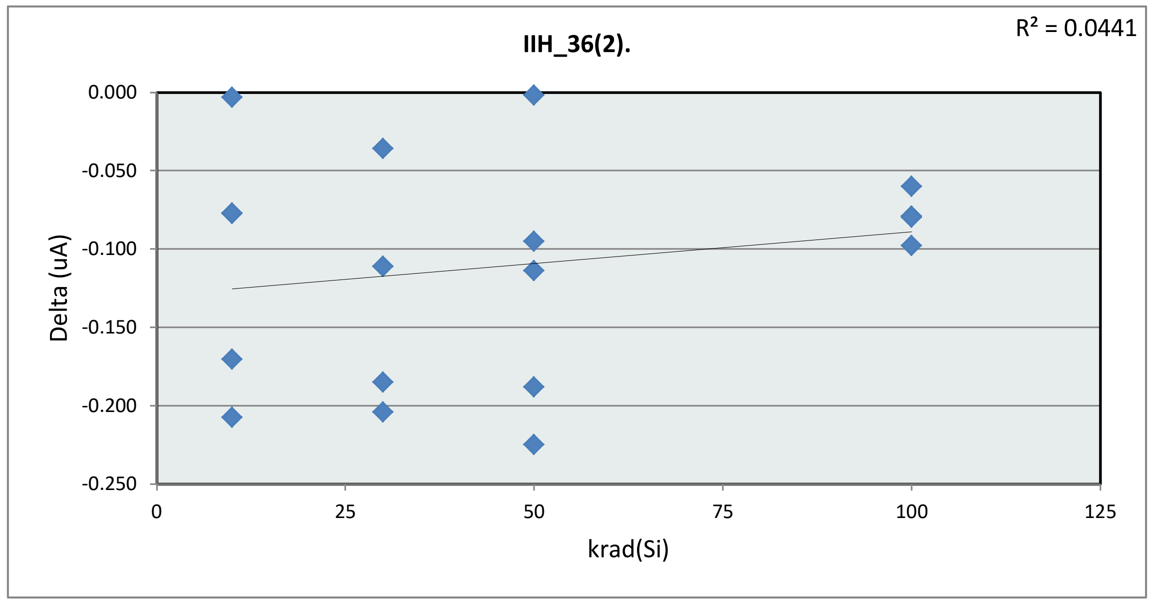
	IIH_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.118	3.155	3.156	3.162
Average	3.196	3.218	3.230	3.196
Max	3.248	3.267	3.286	3.218
UL	25.000	25.000	25.000	25.000



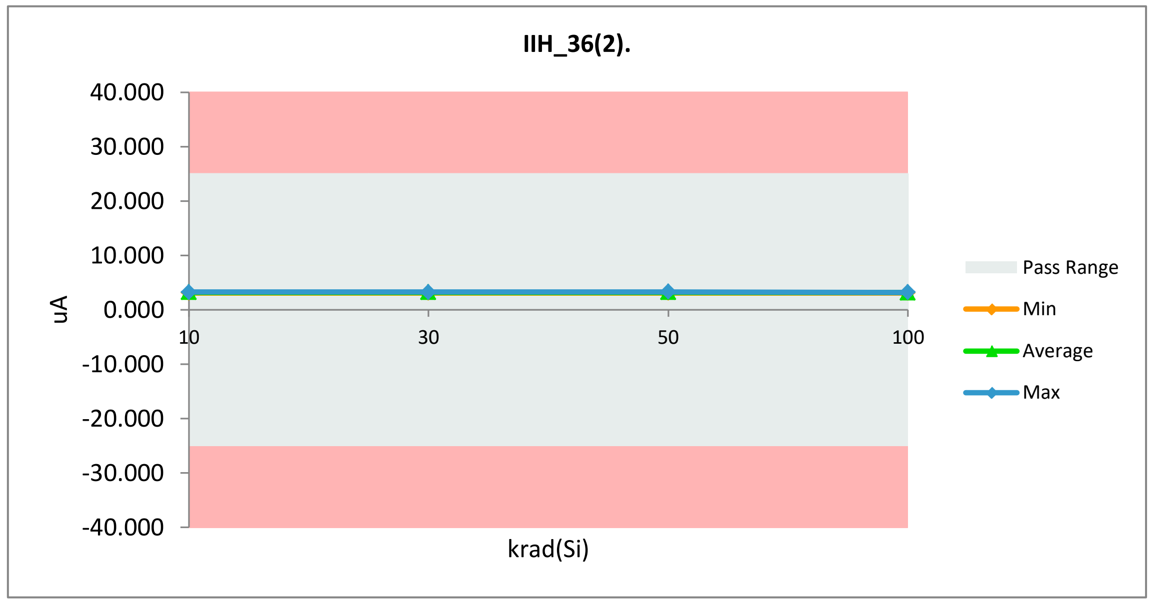
LDR UnBiased TID Report
SN55LVCP22A-SP

	IIH_36(2).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	3.042	3.213	-0.171
10	7	3.098	3.305	-0.207
10	8	3.042	3.120	-0.078
10	9	3.228	3.231	-0.003
10	10	3.191	3.268	-0.077
30	6	3.042	3.227	-0.185
30	7	3.098	3.302	-0.204
30	8	3.042	3.153	-0.111
30	9	3.228	3.264	-0.036
30	10	3.191	3.302	-0.111
50	6	3.042	3.230	-0.188
50	7	3.098	3.323	-0.225
50	8	3.042	3.156	-0.114
50	9	3.228	3.230	-0.002
50	10	3.191	3.286	-0.095
100	B011	3.135	3.233	-0.098
100	B012	3.117	3.196	-0.079
100	B013	3.080	3.140	-0.060
100	B014	3.080	3.159	-0.079
100	B015	3.042	3.122	-0.080
	Max	3.228	3.323	-0.002
	Average	3.113	3.223	-0.110
	Min	3.042	3.120	-0.225
	Std Dev	0.071	0.065	0.066



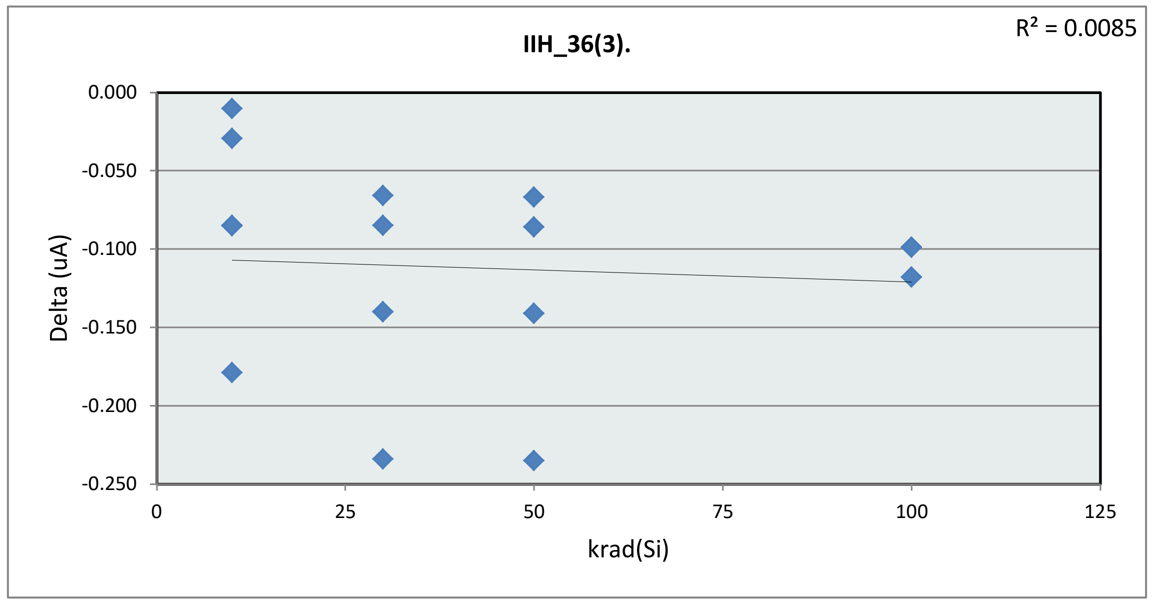
	IIH_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.120	3.153	3.156	3.122
Average	3.227	3.250	3.245	3.170
Max	3.305	3.302	3.323	3.233
UL	25.000	25.000	25.000	25.000



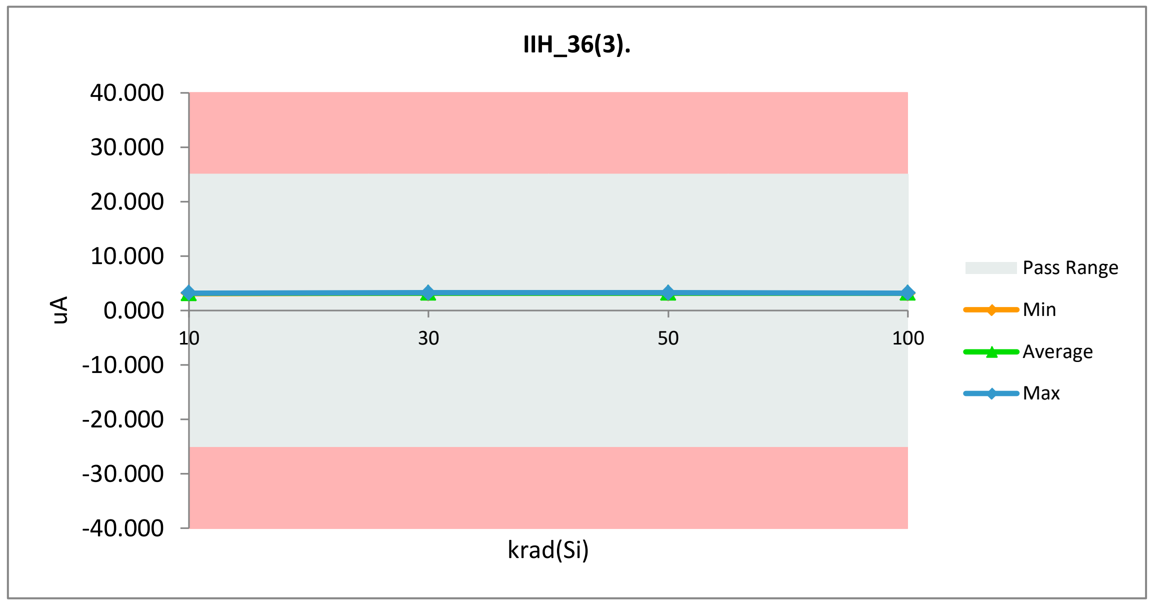
LDR UnBiased TID Report
SN55LVCP22A-SP

	IIH_36(3).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	3.107	3.192	-0.085
10	7	3.069	3.248	-0.179
10	8	3.088	3.117	-0.029
10	9	3.200	3.211	-0.011
10	10	3.144	3.229	-0.085
30	6	3.107	3.247	-0.140
30	7	3.069	3.303	-0.234
30	8	3.088	3.173	-0.085
30	9	3.200	3.266	-0.066
30	10	3.144	3.284	-0.140
50	6	3.107	3.248	-0.141
50	7	3.069	3.304	-0.235
50	8	3.088	3.174	-0.086
50	9	3.200	3.267	-0.067
50	10	3.144	3.285	-0.141
100	B011	3.125	3.243	-0.118
100	B012	3.107	3.225	-0.118
100	B013	3.107	3.206	-0.099
100	B014	3.144	3.243	-0.099
100	B015	3.107	3.206	-0.099
	Max	3.200	3.304	-0.011
	Average	3.121	3.234	-0.113
	Min	3.069	3.117	-0.235
	Std Dev	0.042	0.047	0.057



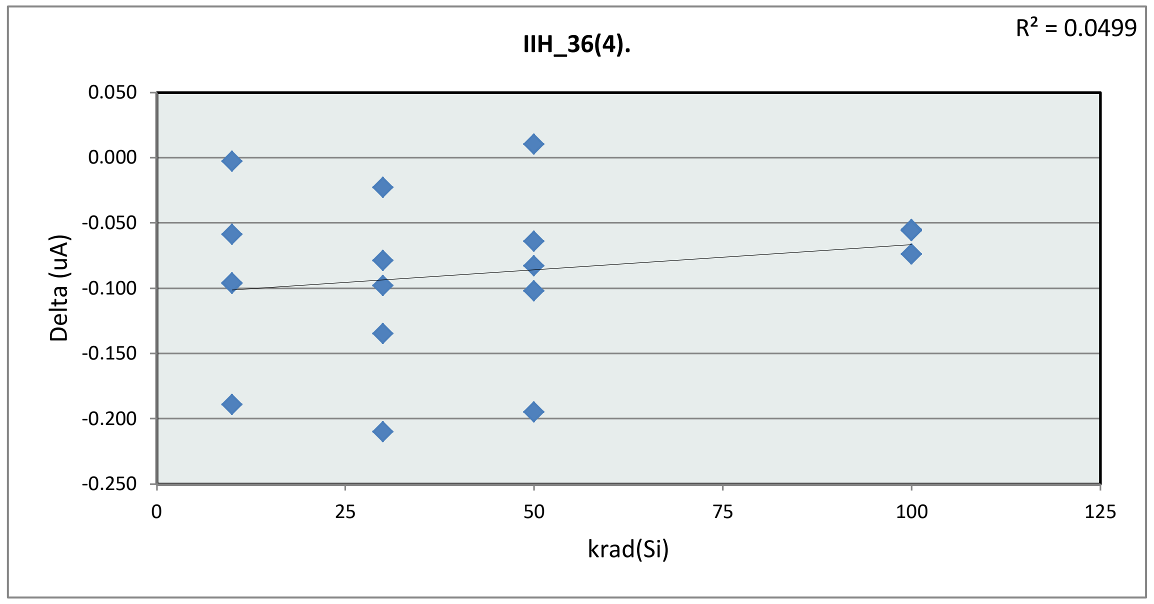
	IIH_36(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.117	3.173	3.174	3.206
Average	3.199	3.255	3.256	3.225
Max	3.248	3.303	3.304	3.243
UL	25.000	25.000	25.000	25.000



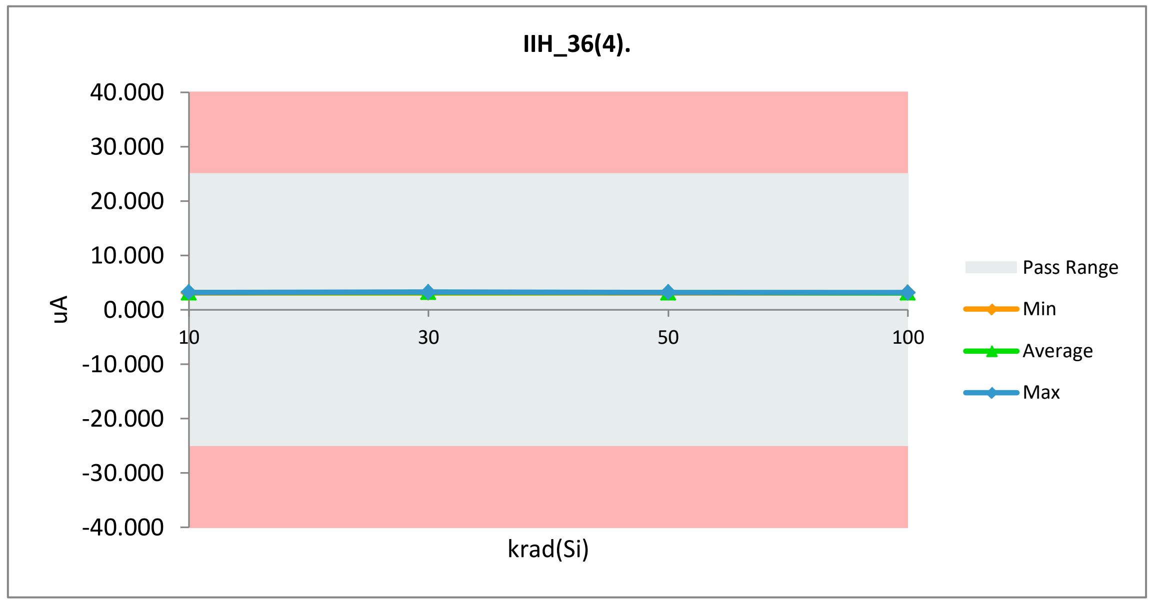
LDR UnBiased TID Report
SN55LVCP22A-SP

	IIH_36(4).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	3.089	3.185	-0.096
10	7	3.052	3.241	-0.189
10	8	3.052	3.111	-0.059
10	9	3.201	3.204	-0.003
10	10	3.145	3.241	-0.096
30	6	3.089	3.224	-0.135
30	7	3.052	3.262	-0.210
30	8	3.052	3.131	-0.079
30	9	3.201	3.224	-0.023
30	10	3.145	3.243	-0.098
50	6	3.089	3.191	-0.102
50	7	3.052	3.247	-0.195
50	8	3.052	3.116	-0.064
50	9	3.201	3.191	0.010
50	10	3.145	3.228	-0.083
100	B011	3.089	3.163	-0.074
100	B012	3.108	3.163	-0.055
100	B013	3.089	3.145	-0.056
100	B014	3.108	3.182	-0.074
100	B015	3.089	3.145	-0.056
	Max	3.201	3.262	0.010
	Average	3.105	3.192	-0.087
	Min	3.052	3.111	-0.210
	Std Dev	0.052	0.047	0.059



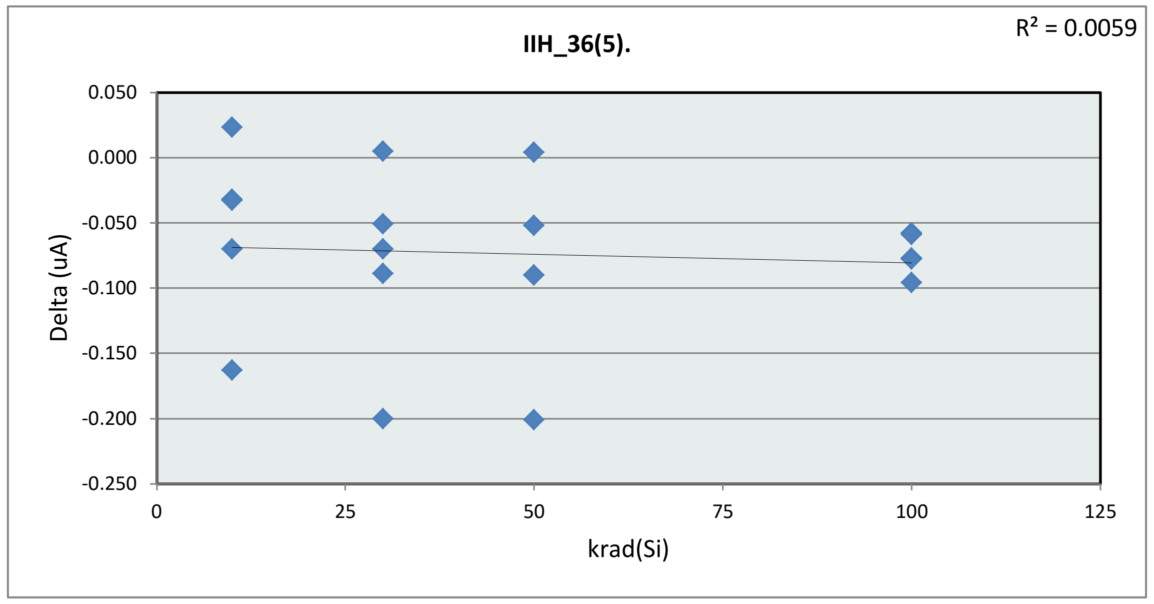
	IIH_36(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.111	3.131	3.116	3.145
Average	3.196	3.217	3.195	3.160
Max	3.241	3.262	3.247	3.182
UL	25.000	25.000	25.000	25.000



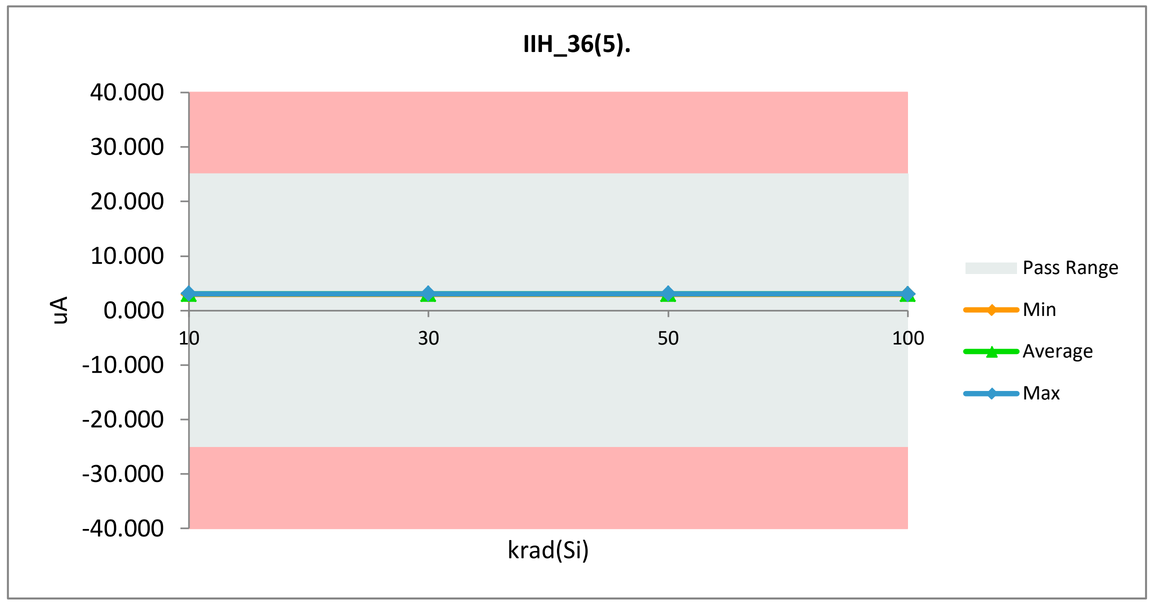
LDR UnBiased TID Report
SN55LVCP22A-SP

	IIH_36(5).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	2.936	3.006	-0.070
10	7	2.899	3.062	-0.163
10	8	2.918	2.950	-0.032
10	9	3.048	3.025	0.023
10	10	2.992	3.025	-0.033
30	6	2.936	3.025	-0.089
30	7	2.899	3.099	-0.200
30	8	2.918	2.969	-0.051
30	9	3.048	3.043	0.005
30	10	2.992	3.062	-0.070
50	6	2.936	3.026	-0.090
50	7	2.899	3.100	-0.201
50	8	2.918	2.970	-0.052
50	9	3.048	3.044	0.004
50	10	2.992	3.082	-0.090
100	B011	2.974	3.051	-0.077
100	B012	2.936	3.032	-0.096
100	B013	2.918	2.976	-0.058
100	B014	2.955	3.014	-0.059
100	B015	2.936	3.014	-0.078
	Max	3.048	3.100	0.023
	Average	2.955	3.029	-0.074
	Min	2.899	2.950	-0.201
	Std Dev	0.050	0.042	0.060



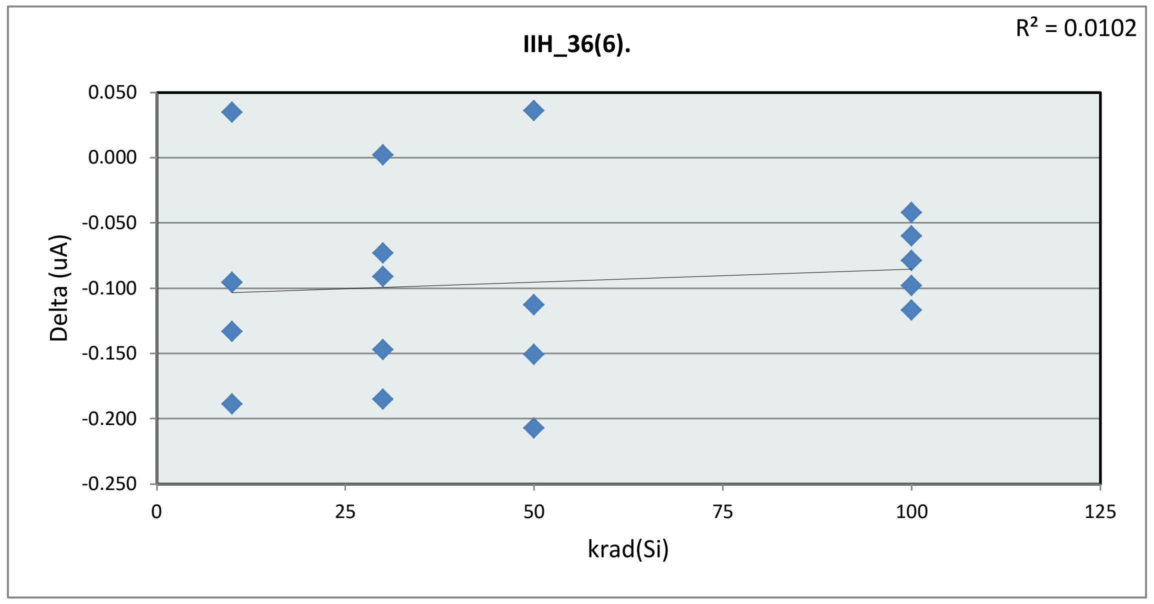
	IIH_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.950	2.969	2.970	2.976
Average	3.014	3.040	3.044	3.017
Max	3.062	3.099	3.100	3.051
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
SN55LVCP22A-SP

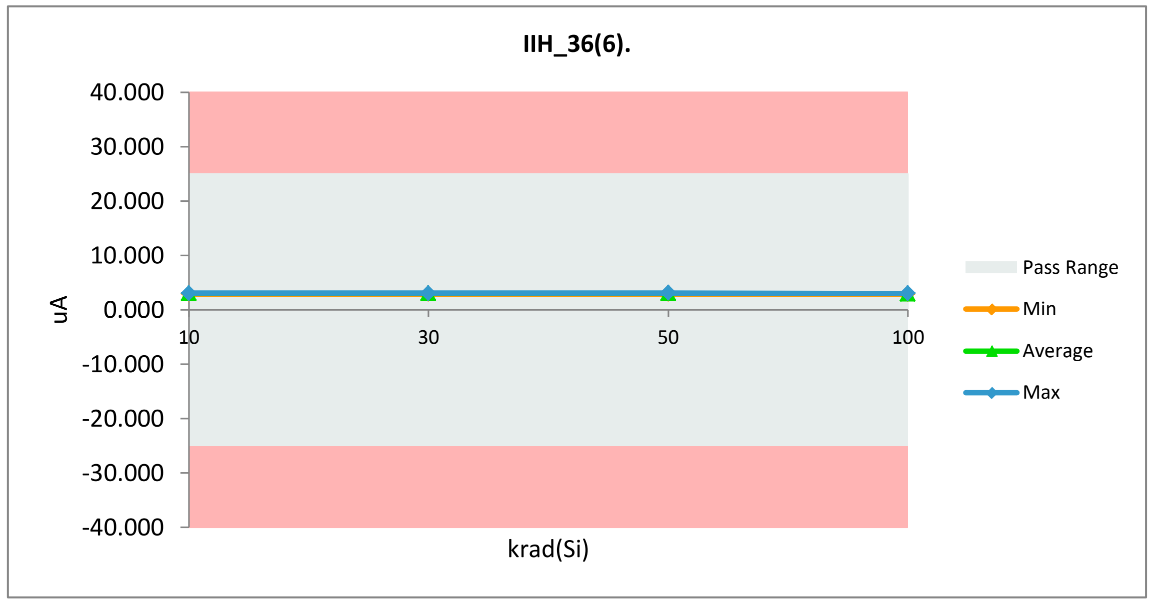
	IIH_36(6).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	2.875	3.008	-0.133
10	7	2.912	3.101	-0.189
10	8	2.838	2.934	-0.096
10	9	3.080	3.045	0.035
10	10	2.968	3.064	-0.096
30	6	2.875	3.022	-0.147
30	7	2.912	3.097	-0.185
30	8	2.838	2.929	-0.091
30	9	3.080	3.078	0.002
30	10	2.968	3.041	-0.073
50	6	2.875	3.026	-0.151
50	7	2.912	3.119	-0.207
50	8	2.838	2.951	-0.113
50	9	3.080	3.044	0.036
50	10	2.968	3.081	-0.113
100	B011	2.987	3.047	-0.060
100	B012	2.912	3.029	-0.117
100	B013	2.875	2.973	-0.098
100	B014	2.912	2.954	-0.042
100	B015	2.875	2.954	-0.079
	Max	3.080	3.119	0.036
	Average	2.929	3.025	-0.096
	Min	2.838	2.929	-0.207
	Std Dev	0.079	0.058	0.067



	IIH_36(6).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

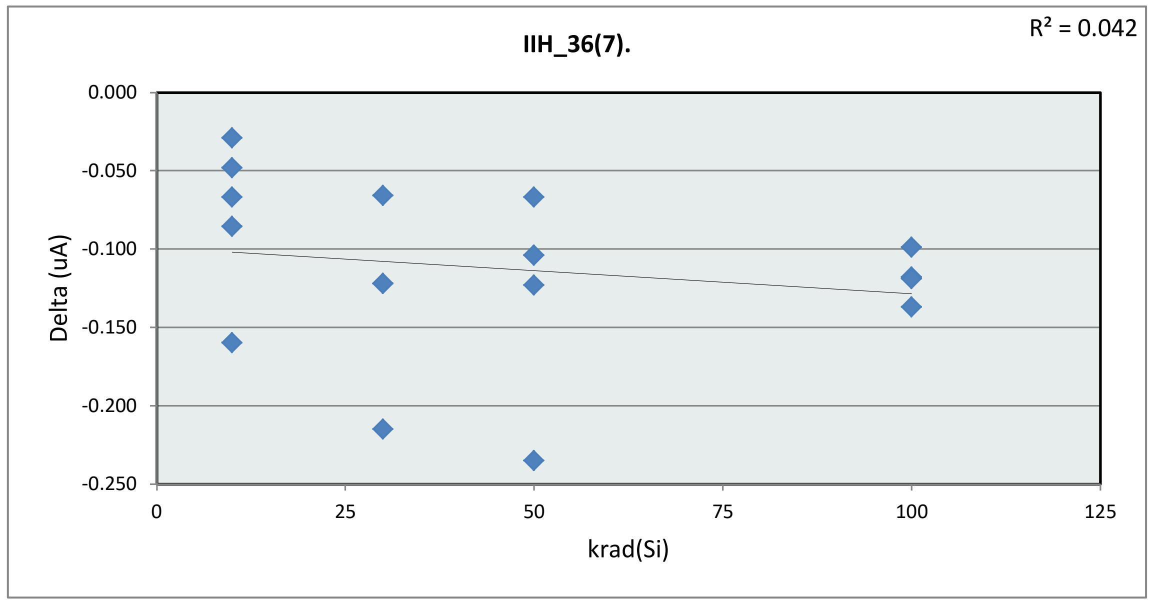
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.934	2.929	2.951	2.954
Average	3.030	3.033	3.044	2.991
Max	3.101	3.097	3.119	3.047
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
SN55LVCP22A-SP

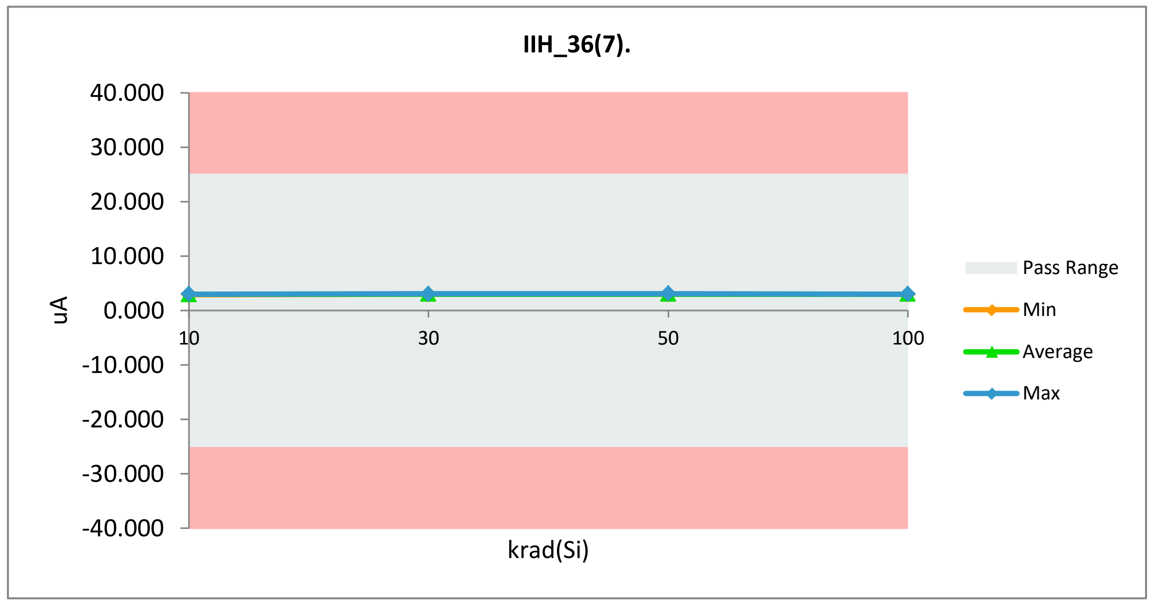
	IIH_36(7).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	2.920	3.006	-0.086
10	7	2.883	3.043	-0.160
10	8	2.883	2.931	-0.048
10	9	2.995	3.024	-0.029
10	10	2.976	3.043	-0.067
30	6	2.920	3.042	-0.122
30	7	2.883	3.098	-0.215
30	8	2.883	3.005	-0.122
30	9	2.995	3.061	-0.066
30	10	2.976	3.098	-0.122
50	6	2.920	3.043	-0.123
50	7	2.883	3.118	-0.235
50	8	2.883	2.987	-0.104
50	9	2.995	3.062	-0.067
50	10	2.976	3.080	-0.104
100	B011	2.939	3.057	-0.118
100	B012	2.902	3.039	-0.137
100	B013	2.902	3.001	-0.099
100	B014	2.939	3.057	-0.118
100	B015	2.920	3.039	-0.119
	Max	2.995	3.118	-0.029
	Average	2.929	3.042	-0.113
	Min	2.883	2.931	-0.235
	Std Dev	0.043	0.043	0.050



	IIH_36(7).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	uA
Min Limit	-25	uA

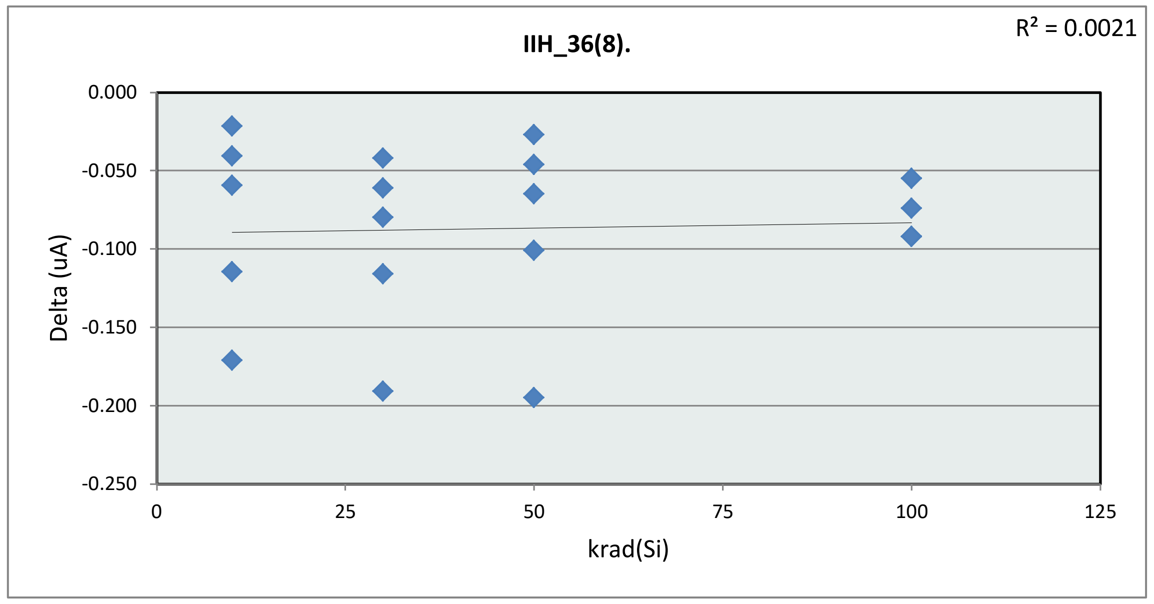
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.931	3.005	2.987	3.001
Average	3.009	3.061	3.058	3.039
Max	3.043	3.098	3.118	3.057
UL	25.000	25.000	25.000	25.000



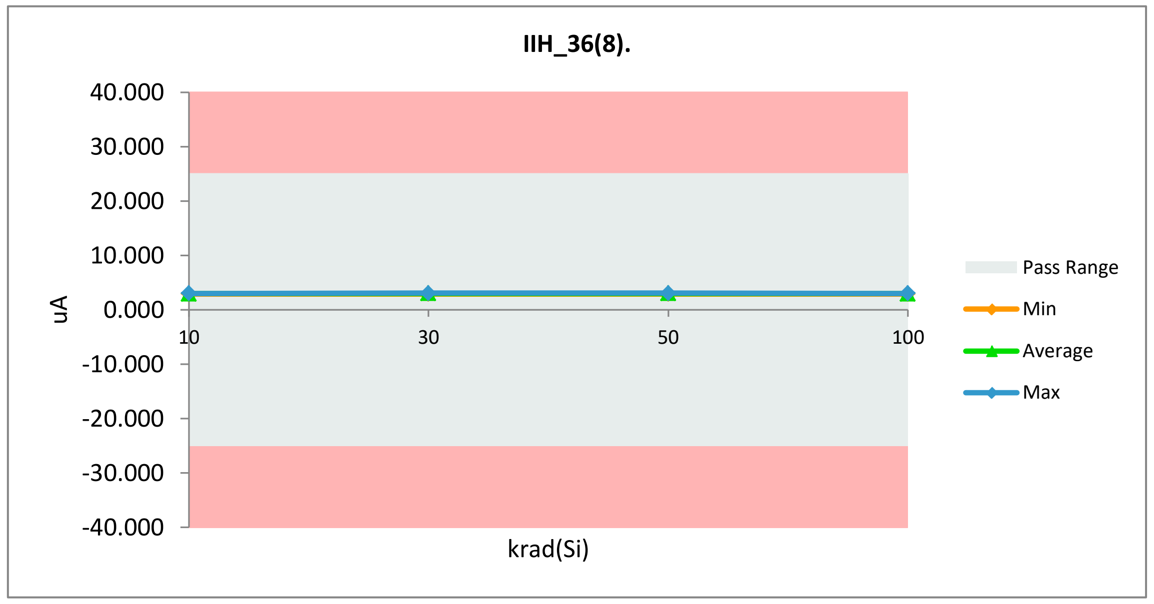
LDR UnBiased TID Report
SN55LVCP22A-SP

	IIH_36(8).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	2.903	3.018	-0.115
10	7	2.884	3.055	-0.171
10	8	2.884	2.925	-0.041
10	9	2.996	3.018	-0.022
10	10	2.977	3.036	-0.059
30	6	2.903	3.019	-0.116
30	7	2.884	3.075	-0.191
30	8	2.884	2.945	-0.061
30	9	2.996	3.038	-0.042
30	10	2.977	3.057	-0.080
50	6	2.903	3.004	-0.101
50	7	2.884	3.079	-0.195
50	8	2.884	2.930	-0.046
50	9	2.996	3.023	-0.027
50	10	2.977	3.042	-0.065
100	B011	2.922	3.014	-0.092
100	B012	2.903	2.995	-0.092
100	B013	2.884	2.958	-0.074
100	B014	2.940	2.995	-0.055
100	B015	2.903	2.995	-0.092
	Max	2.996	3.079	-0.022
	Average	2.924	3.011	-0.087
	Min	2.884	2.925	-0.195
	Std Dev	0.045	0.044	0.050

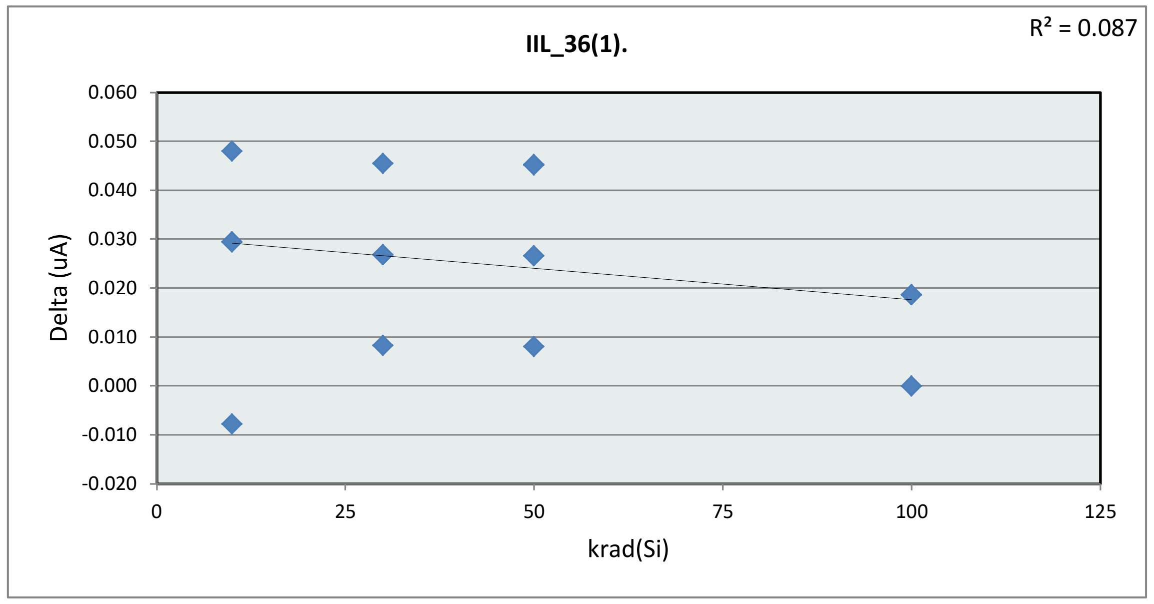


	IIH_36(8).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	uA		
Min Limit	-25	uA		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.925	2.945	2.930	2.958
Average	3.010	3.027	3.016	2.991
Max	3.055	3.075	3.079	3.014
UL	25.000	25.000	25.000	25.000

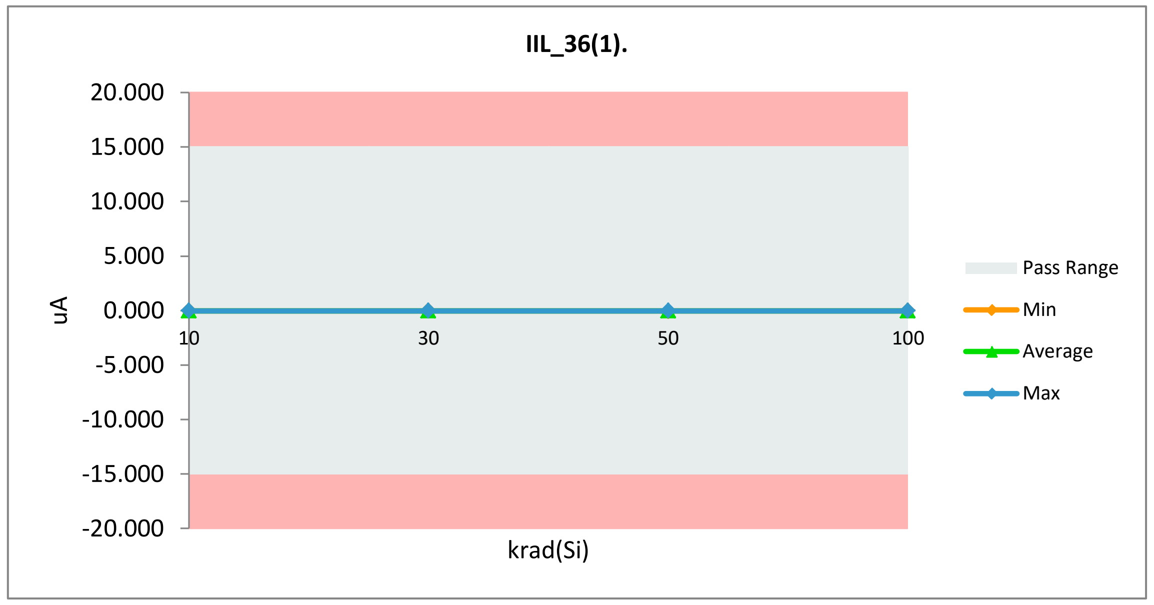


LDR UnBiased TID Report
SN55LVCP22A-SP

		IIL_36(1).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbias	Delta
10	6	-0.002	-0.031	0.029
10	7	-0.002	-0.031	0.029
10	8	-0.002	-0.031	0.029
10	9	0.017	-0.031	0.048
10	10	-0.020	-0.012	-0.008
30	6	-0.002	-0.029	0.027
30	7	-0.002	-0.029	0.027
30	8	-0.002	-0.029	0.027
30	9	0.017	-0.029	0.045
30	10	-0.020	-0.029	0.008
50	6	-0.002	-0.028	0.027
50	7	-0.002	-0.028	0.027
50	8	-0.002	-0.047	0.045
50	9	0.017	-0.028	0.045
50	10	-0.020	-0.028	0.008
100	B011	-0.020	-0.020	0.000
100	B012	-0.002	-0.020	0.019
100	B013	-0.002	-0.020	0.019
100	B014	-0.002	-0.020	0.019
100	B015	-0.002	-0.020	0.019
	Max	0.017	-0.012	0.048
	Average	-0.003	-0.027	0.024
	Min	-0.020	-0.047	-0.008
	Std Dev	0.011	0.007	0.015

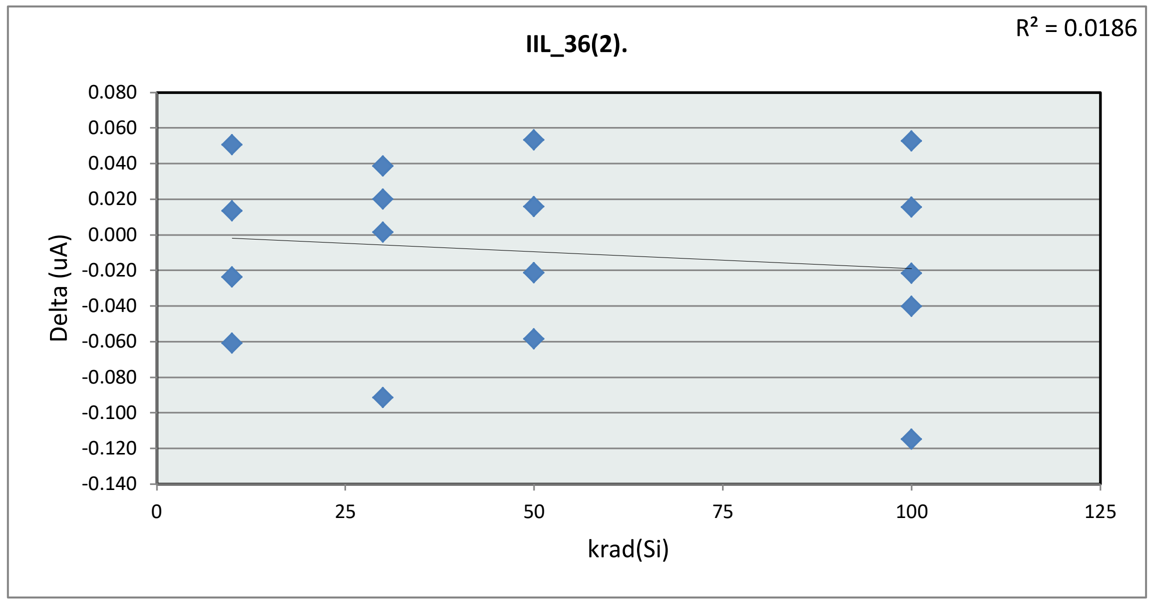


	IIL_36(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.031	-0.029	-0.047	-0.020
Average	-0.027	-0.029	-0.032	-0.020
Max	-0.012	-0.029	-0.028	-0.020
UL	15.000	15.000	15.000	15.000

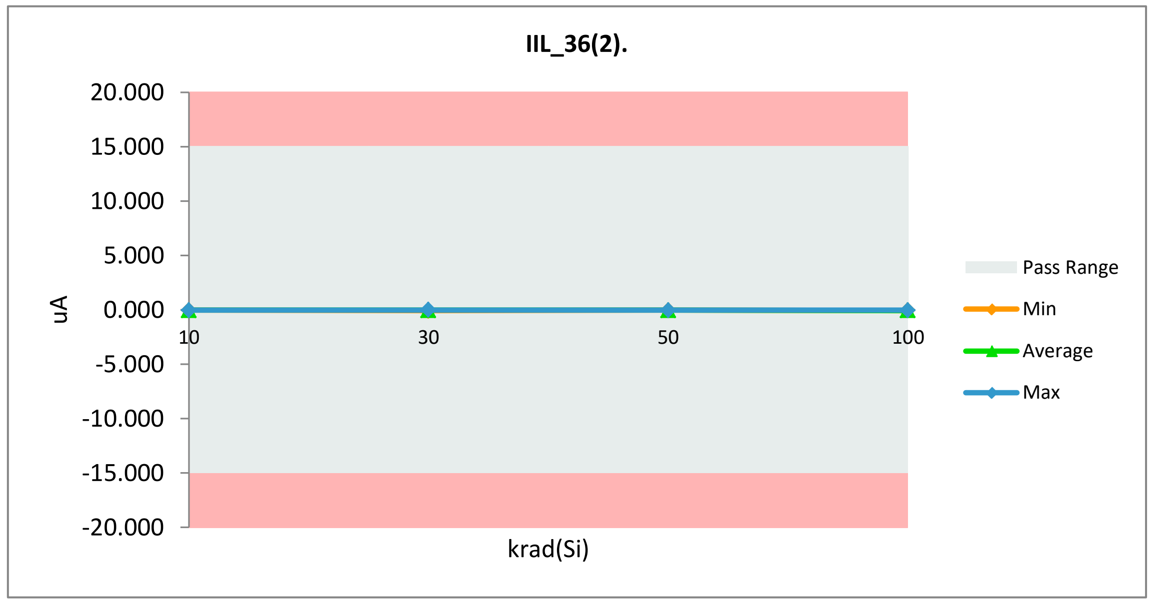


LDR UnBiased TID Report
SN55LVCP22A-SP

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
		IIL_36(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
10	6	-0.046	-0.022	-0.024
10	7	-0.009	-0.022	0.013
10	8	-0.083	-0.022	-0.061
10	9	-0.046	-0.022	-0.024
10	10	0.029	-0.022	0.051
30	6	-0.046	-0.084	0.039
30	7	-0.009	-0.047	0.039
30	8	-0.083	0.009	-0.092
30	9	-0.046	-0.047	0.001
30	10	0.029	0.009	0.020
50	6	-0.046	-0.024	-0.021
50	7	-0.009	-0.024	0.016
50	8	-0.083	-0.024	-0.059
50	9	-0.046	-0.024	-0.021
50	10	0.029	-0.024	0.053
100	B011	-0.027	-0.043	0.015
100	B012	-0.083	-0.043	-0.040
100	B013	0.010	-0.043	0.053
100	B014	-0.157	-0.043	-0.115
100	B015	-0.046	-0.024	-0.022
	Max	0.029	0.009	0.053
	Average	-0.038	-0.029	-0.009
	Min	-0.157	-0.084	-0.115
	Std Dev	0.047	0.020	0.048



	IIL_36(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.022	-0.084	-0.024	-0.043
Average	-0.022	-0.032	-0.024	-0.039
Max	-0.022	0.009	-0.024	-0.024
UL	15.000	15.000	15.000	15.000



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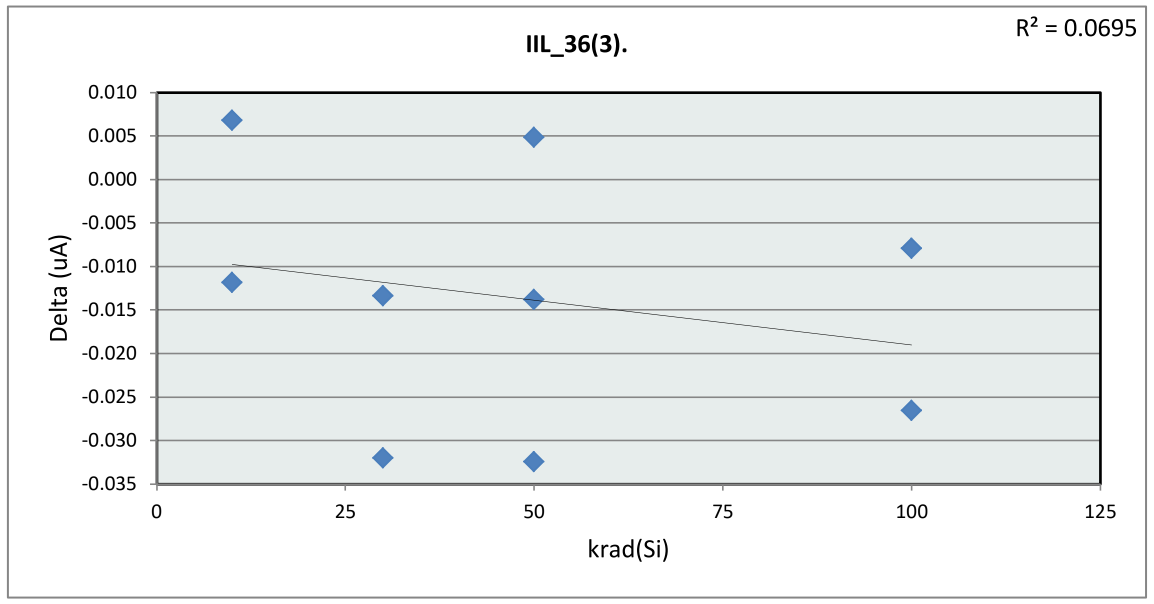
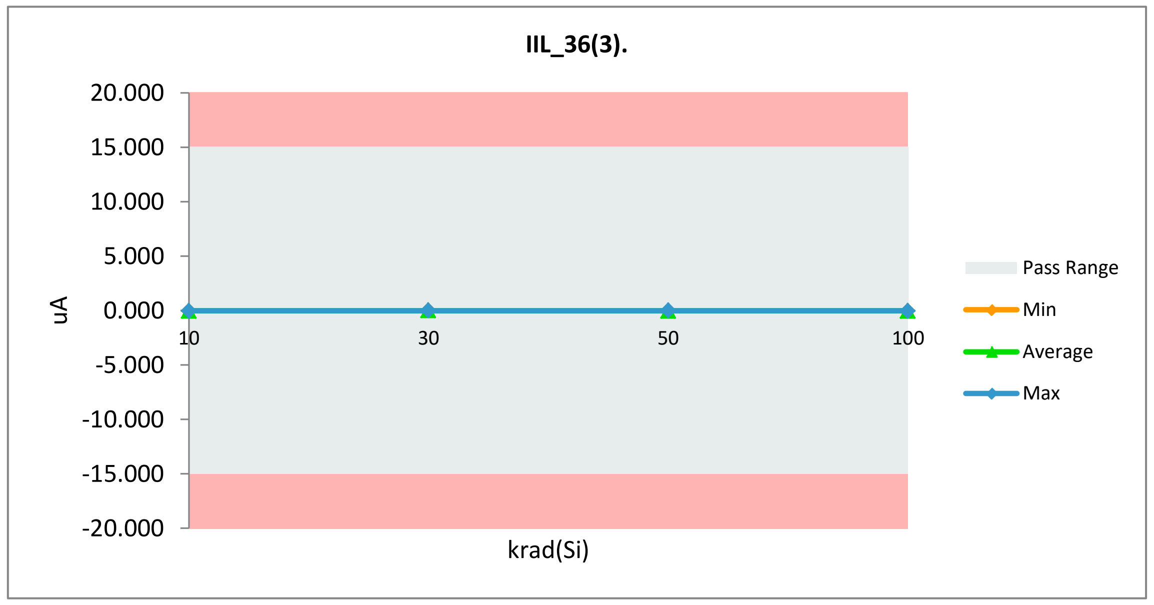
	IIL_36(3).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	-0.023	-0.030	0.007
10	7	-0.042	-0.030	-0.012
10	8	-0.023	-0.030	0.007
10	9	-0.023	-0.030	0.007
10	10	-0.042	-0.030	-0.012
30	6	-0.023	-0.010	-0.013
30	7	-0.042	-0.010	-0.032
30	8	-0.023	-0.010	-0.013
30	9	-0.023	-0.010	-0.013
30	10	-0.042	-0.010	-0.032
50	6	-0.023	-0.028	0.005
50	7	-0.042	-0.010	-0.032
50	8	-0.023	-0.010	-0.014
50	9	-0.023	-0.010	-0.014
50	10	-0.042	-0.010	-0.032
100	B011	-0.042	-0.016	-0.027
100	B012	-0.023	-0.016	-0.008
100	B013	-0.023	-0.016	-0.008
100	B014	-0.042	-0.016	-0.027
100	B015	-0.023	-0.016	-0.008
	Max	-0.023	-0.010	0.007
	Average	-0.031	-0.017	-0.014
	Min	-0.042	-0.030	-0.032
	Std Dev	0.009	0.009	0.013



	IIL_36(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.030	-0.010	-0.028	-0.016
Average	-0.030	-0.010	-0.013	-0.016
Max	-0.030	-0.010	-0.010	-0.016
UL	15.000	15.000	15.000	15.000



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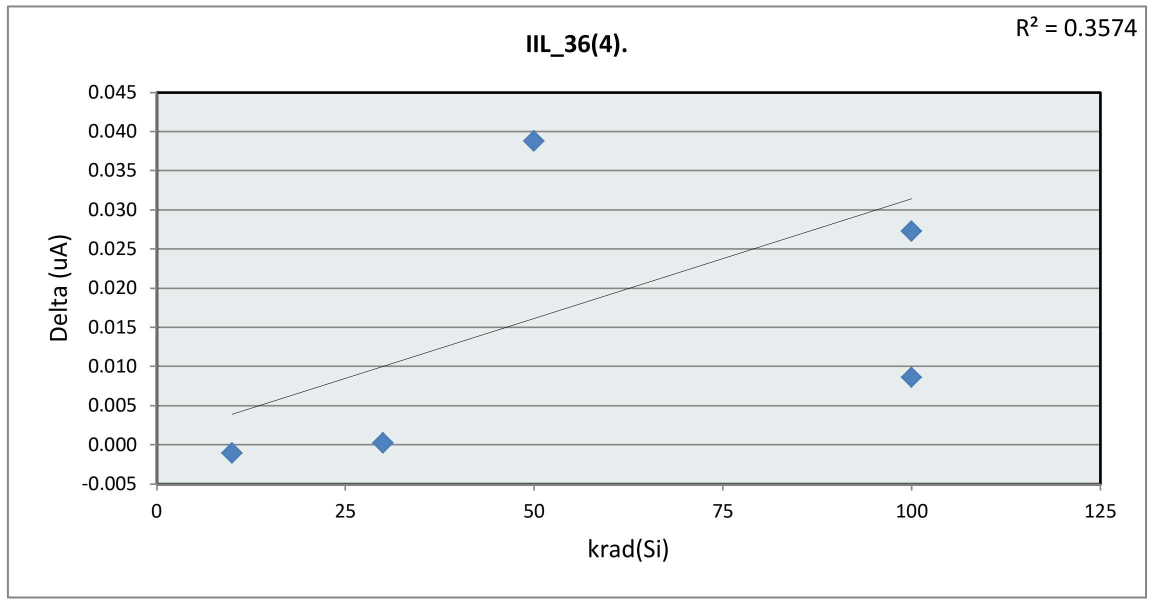
SN55LVCP22A-SP

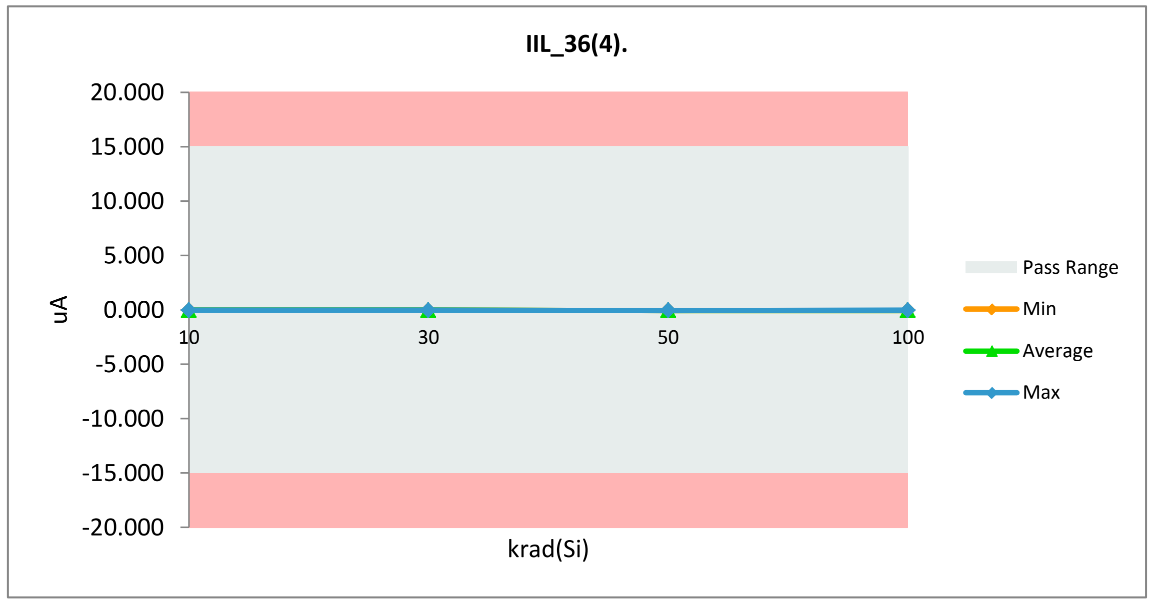
	IIL_36(4).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.019	-0.018	-0.001
10	7	-0.019	-0.018	-0.001
10	8	-0.019	-0.018	-0.001
10	9	-0.019	-0.018	-0.001
10	10	-0.019	-0.018	-0.001
30	6	-0.019	-0.019	0.000
30	7	-0.019	-0.019	0.000
30	8	-0.019	-0.019	0.000
30	9	-0.019	-0.019	0.000
30	10	-0.019	-0.019	0.000
50	6	-0.019	-0.057	0.039
50	7	-0.019	-0.057	0.039
50	8	-0.019	-0.057	0.039
50	9	-0.019	-0.057	0.039
50	10	-0.019	-0.057	0.039
100	B011	-0.019	-0.046	0.027
100	B012	-0.019	-0.046	0.027
100	B013	-0.019	-0.046	0.027
100	B014	-0.019	-0.027	0.009
100	B015	-0.019	-0.046	0.027
	Max	-0.019	-0.018	0.039
	Average	-0.019	-0.034	0.015
	Min	-0.019	-0.057	-0.001
	Std Dev	0.000	0.018	0.018



	IIL_36(4).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	15	uA
Min Limit	-15	uA

krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	-0.018	-0.019	-0.057	-0.046
Average	-0.018	-0.019	-0.057	-0.042
Max	-0.018	-0.019	-0.057	-0.027
UL	15.000	15.000	15.000	15.000



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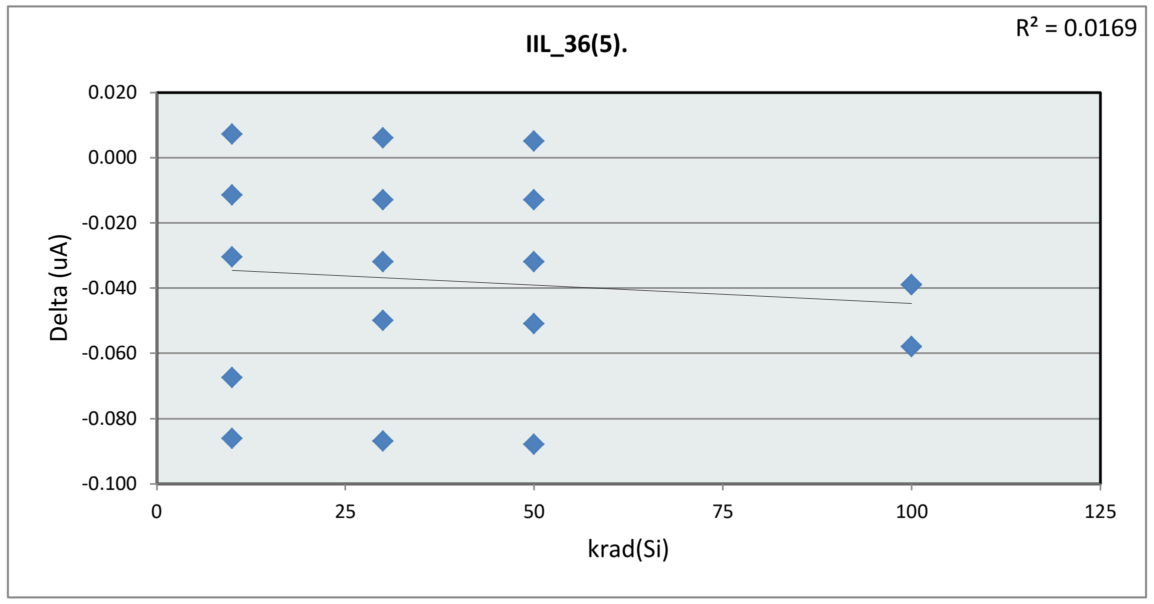
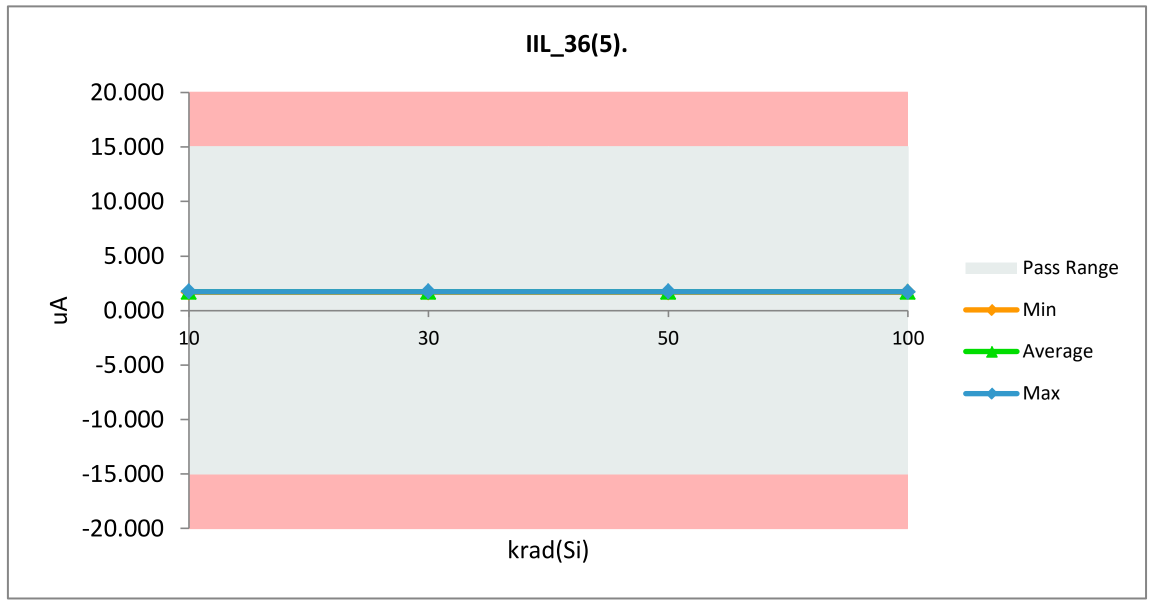
	IIL_36(5).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-15	-15

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.653	1.720	-0.067
10	7	1.653	1.739	-0.086
10	8	1.653	1.665	-0.012
10	9	1.709	1.702	0.007
10	10	1.690	1.720	-0.030
30	6	1.653	1.703	-0.050
30	7	1.653	1.740	-0.087
30	8	1.653	1.666	-0.013
30	9	1.709	1.703	0.006
30	10	1.690	1.722	-0.032
50	6	1.653	1.704	-0.051
50	7	1.653	1.741	-0.088
50	8	1.653	1.666	-0.013
50	9	1.709	1.704	0.005
50	10	1.690	1.722	-0.032
100	B011	1.672	1.711	-0.039
100	B012	1.653	1.711	-0.058
100	B013	1.653	1.692	-0.039
100	B014	1.672	1.711	-0.039
100	B015	1.653	1.711	-0.058
	Max	1.709	1.741	0.007
	Average	1.669	1.708	-0.039
	Min	1.653	1.665	-0.088
	Std Dev	0.022	0.022	0.030



	IIL_36(5).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.665	1.666	1.666	1.692
Average	1.709	1.707	1.707	1.707
Max	1.739	1.740	1.741	1.711
UL	15.000	15.000	15.000	15.000



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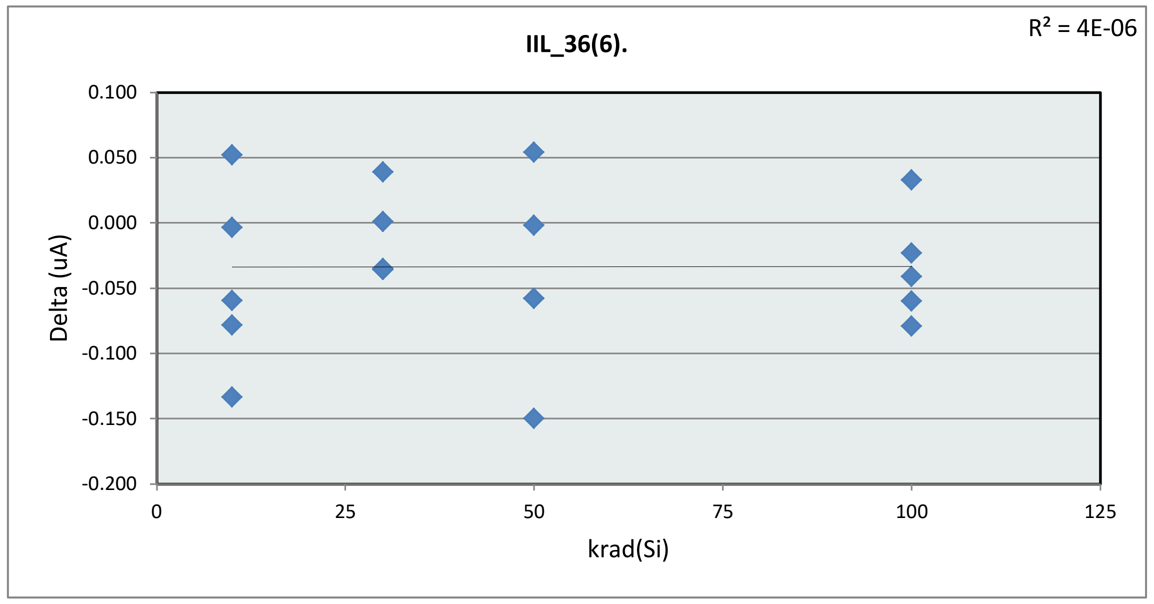
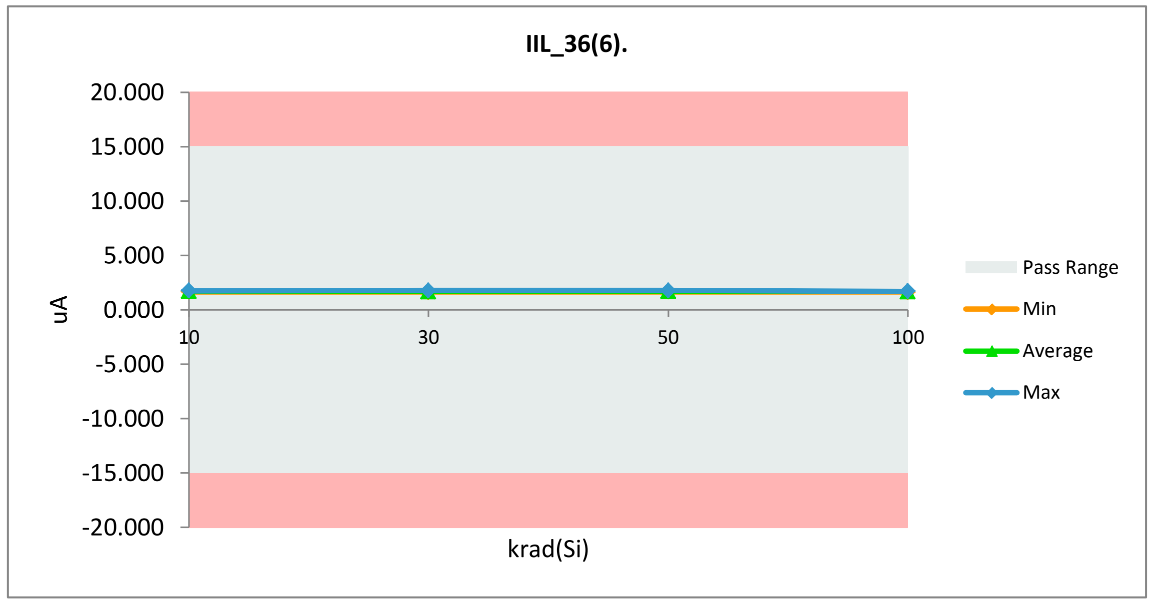
		IIL_36(6).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.647	1.725	-0.078
10	7	1.629	1.763	-0.134
10	8	1.610	1.670	-0.060
10	9	1.722	1.725	-0.003
10	10	1.796	1.744	0.052
30	6	1.647	1.683	-0.036
30	7	1.629	1.664	-0.035
30	8	1.610	1.646	-0.036
30	9	1.722	1.683	0.039
30	10	1.796	1.795	0.001
50	6	1.647	1.705	-0.058
50	7	1.629	1.779	-0.150
50	8	1.610	1.668	-0.058
50	9	1.722	1.724	-0.002
50	10	1.796	1.742	0.054
100	B011	1.666	1.707	-0.041
100	B012	1.647	1.707	-0.060
100	B013	1.591	1.670	-0.079
100	B014	1.684	1.651	0.033
100	B015	1.647	1.670	-0.023
	Max	1.796	1.795	0.054
	Average	1.672	1.706	-0.034
	Min	1.591	1.646	-0.150
	Std Dev	0.065	0.043	0.055



	IIL_36(6).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.670	1.646	1.668	1.651
Average	1.725	1.694	1.724	1.681
Max	1.763	1.795	1.779	1.707
UL	15.000	15.000	15.000	15.000



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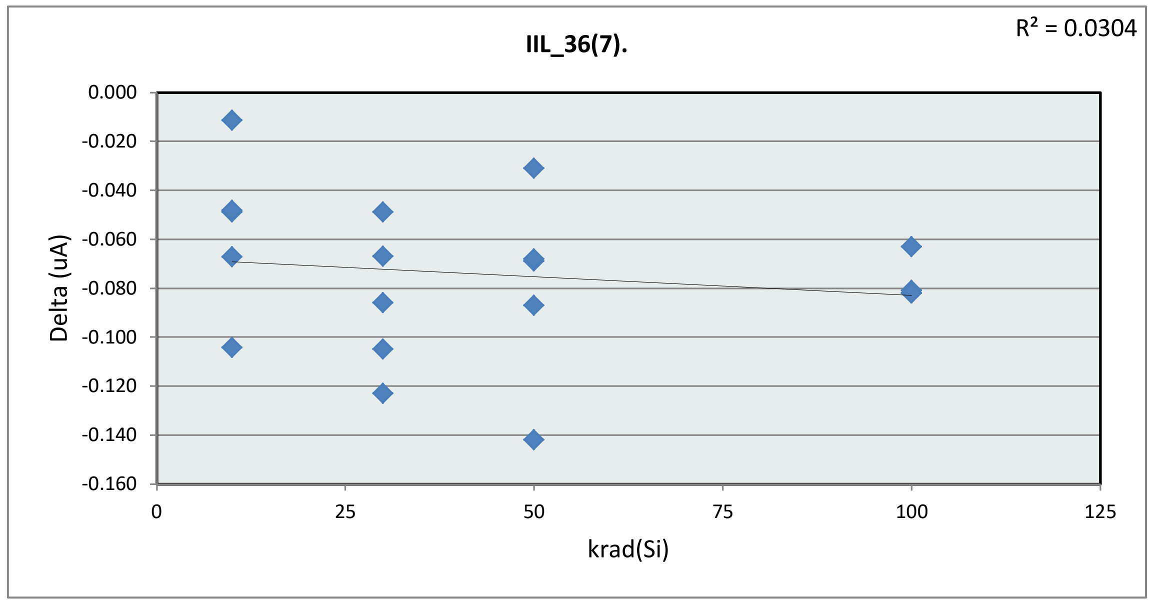
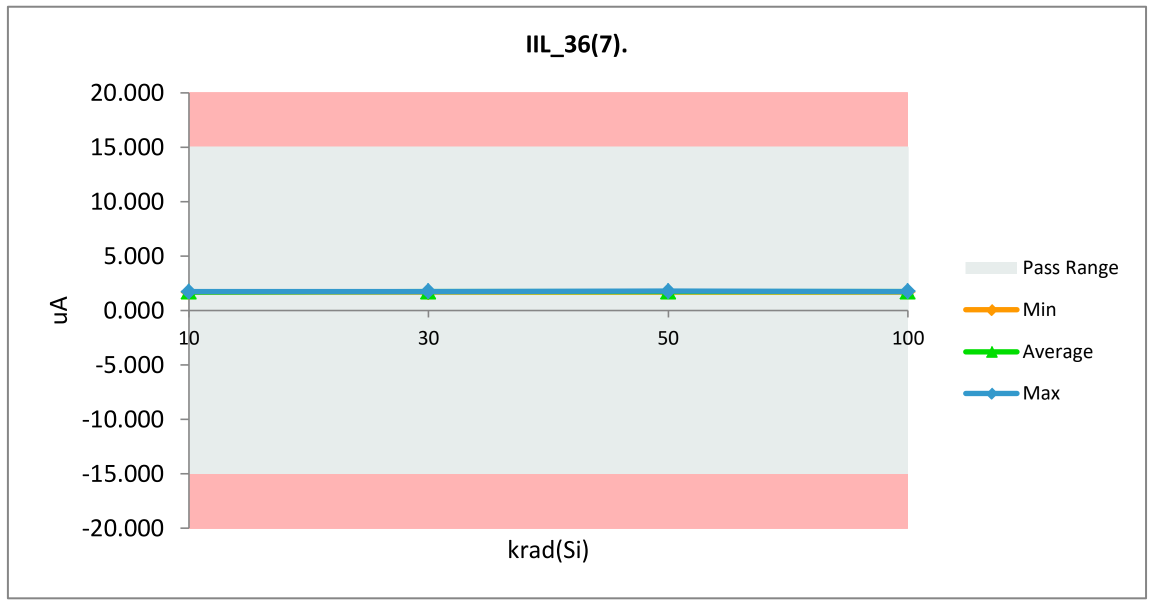
		IIL_36(7).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	15	15	
	Min Limit	-15	-15	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.653	1.702	-0.049
10	7	1.635	1.739	-0.104
10	8	1.635	1.683	-0.048
10	9	1.709	1.721	-0.012
10	10	1.672	1.739	-0.067
30	6	1.653	1.758	-0.105
30	7	1.635	1.758	-0.123
30	8	1.635	1.702	-0.067
30	9	1.709	1.758	-0.049
30	10	1.672	1.758	-0.086
50	6	1.653	1.722	-0.069
50	7	1.635	1.777	-0.142
50	8	1.635	1.703	-0.068
50	9	1.709	1.740	-0.031
50	10	1.672	1.759	-0.087
100	B011	1.672	1.754	-0.082
100	B012	1.653	1.735	-0.082
100	B013	1.635	1.716	-0.081
100	B014	1.672	1.735	-0.063
100	B015	1.653	1.735	-0.082
	Max	1.709	1.777	-0.012
	Average	1.660	1.735	-0.075
	Min	1.635	1.683	-0.142
	Std Dev	0.026	0.025	0.030



	IIL_36(7).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	15	uA		
Min Limit	-15	uA		
krad(Si)	10	30	50	100
LL	-15.000	-15.000	-15.000	-15.000
Min	1.683	1.702	1.703	1.716
Average	1.717	1.747	1.740	1.735
Max	1.739	1.758	1.777	1.754
UL	15.000	15.000	15.000	15.000



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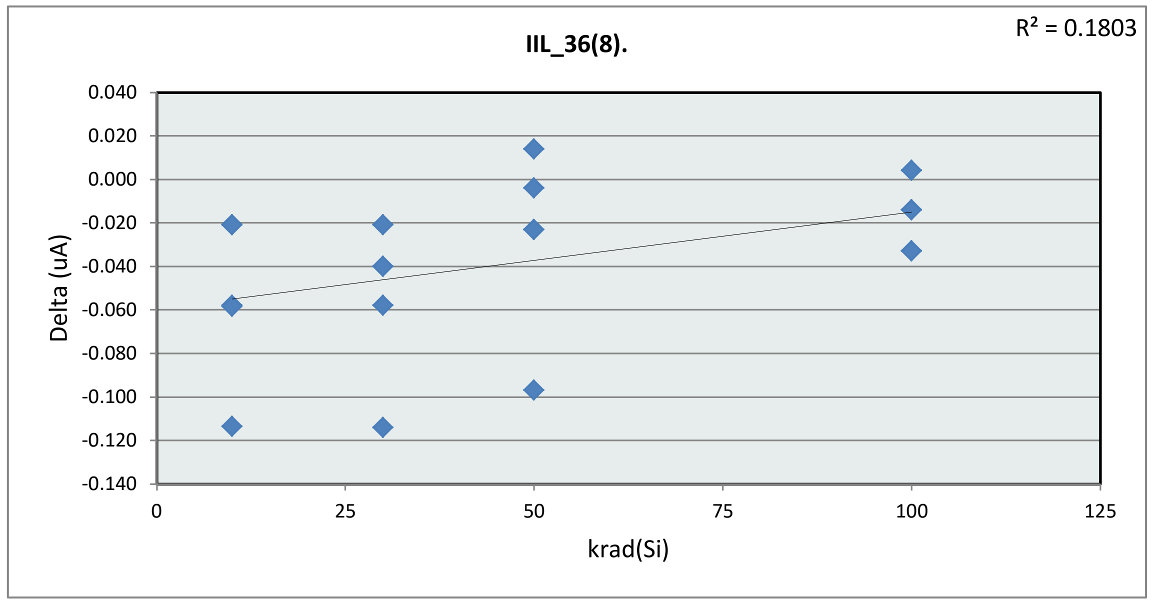
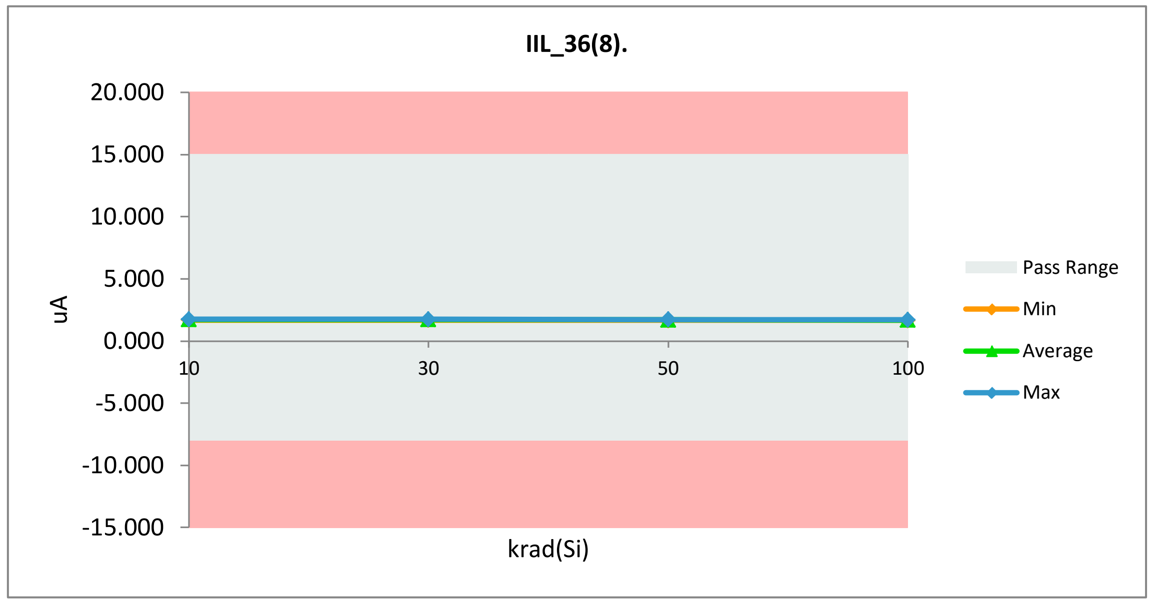
	IIL_36(8).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	15	15
Min Limit	-8	-8

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.675	1.733	-0.058
10	7	1.638	1.751	-0.113
10	8	1.656	1.677	-0.021
10	9	1.712	1.733	-0.021
10	10	1.693	1.751	-0.058
30	6	1.675	1.733	-0.058
30	7	1.638	1.752	-0.114
30	8	1.656	1.696	-0.040
30	9	1.712	1.733	-0.021
30	10	1.693	1.733	-0.040
50	6	1.675	1.698	-0.023
50	7	1.638	1.735	-0.097
50	8	1.656	1.660	-0.004
50	9	1.712	1.698	0.014
50	10	1.693	1.716	-0.023
100	B011	1.675	1.708	-0.033
100	B012	1.675	1.689	-0.014
100	B013	1.675	1.671	0.004
100	B014	1.675	1.708	-0.033
100	B015	1.675	1.689	-0.014
	Max	1.712	1.752	0.014
	Average	1.675	1.713	-0.038
	Min	1.638	1.660	-0.114
	Std Dev	0.023	0.028	0.036



	IIL_36(8).	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	15	uA
Min Limit	-8	uA

krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	1.677	1.696	1.660	1.671
Average	1.729	1.729	1.701	1.693
Max	1.751	1.752	1.735	1.708
UL	15.000	15.000	15.000	15.000



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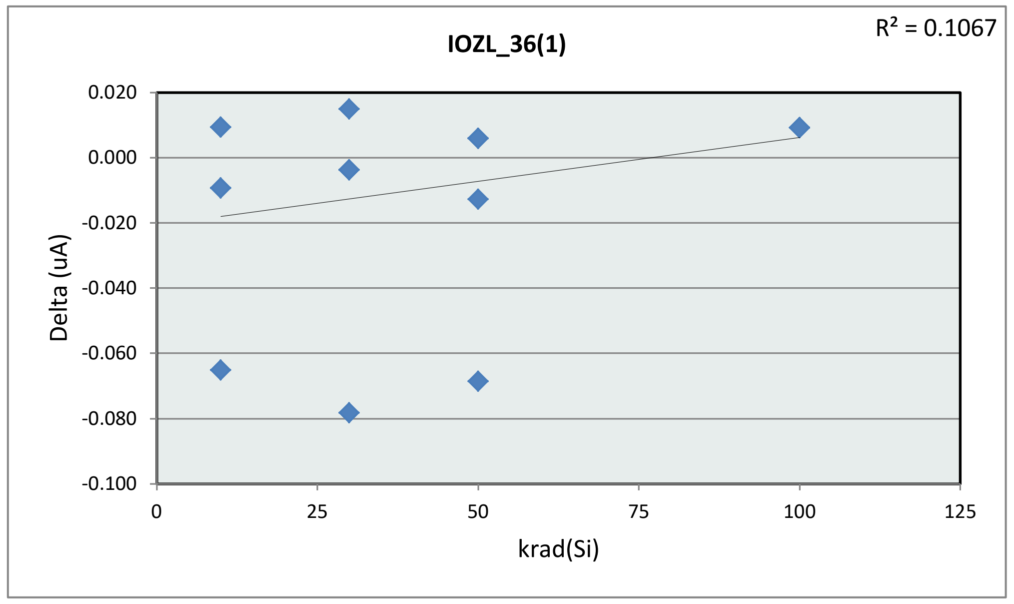
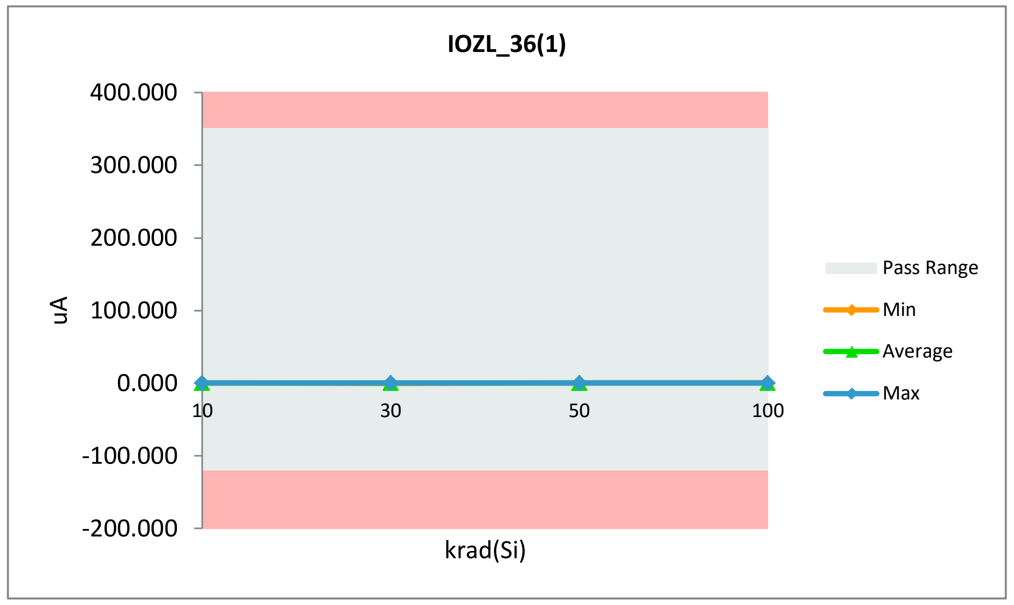
	IOZL_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.012	0.021	-0.009
10	7	-0.063	0.002	-0.065
10	8	0.012	0.021	-0.009
10	9	0.012	0.002	0.009
10	10	0.012	0.002	0.009
30	6	0.012	0.016	-0.004
30	7	-0.063	0.016	-0.078
30	8	0.012	0.016	-0.004
30	9	0.012	-0.003	0.015
30	10	0.012	0.016	-0.004
50	6	0.012	0.025	-0.013
50	7	-0.063	0.006	-0.069
50	8	0.012	0.006	0.006
50	9	0.012	0.006	0.006
50	10	0.012	0.006	0.006
100	B011	0.012	0.003	0.009
100	B012	0.012	0.003	0.009
100	B013	0.012	0.003	0.009
100	B014	0.012	0.003	0.009
100	B015	0.012	0.003	0.009
	Max	0.012	0.025	0.015
	Average	0.001	0.008	-0.008
	Min	-0.063	-0.003	-0.078
	Std Dev	0.027	0.008	0.028



	IOZL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.002	-0.003	0.006	0.003
Average	0.010	0.012	0.010	0.003
Max	0.021	0.016	0.025	0.003
UL	350.000	350.000	350.000	350.000



LDR UnBiased TID Report
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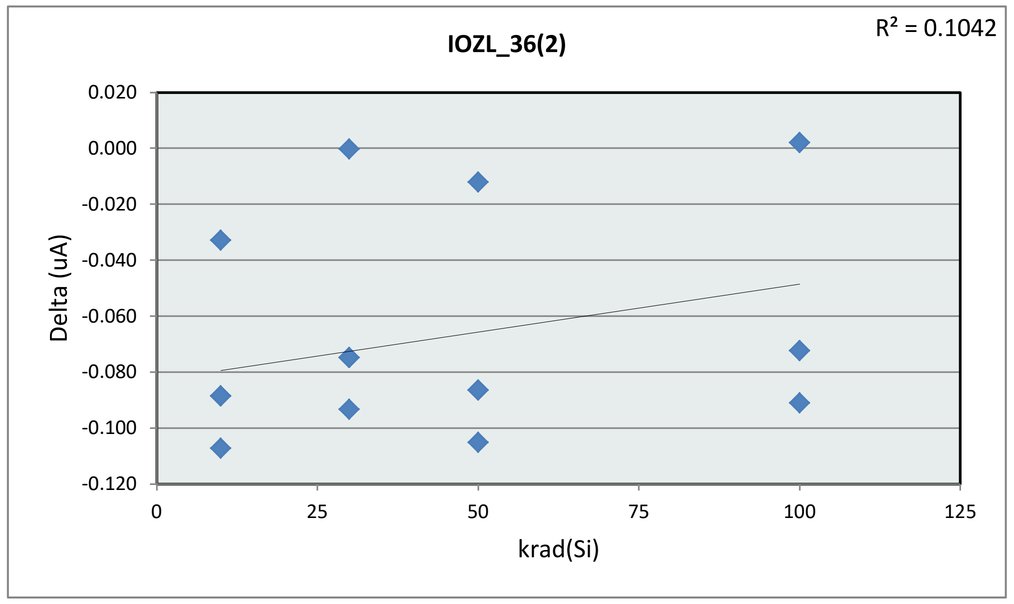
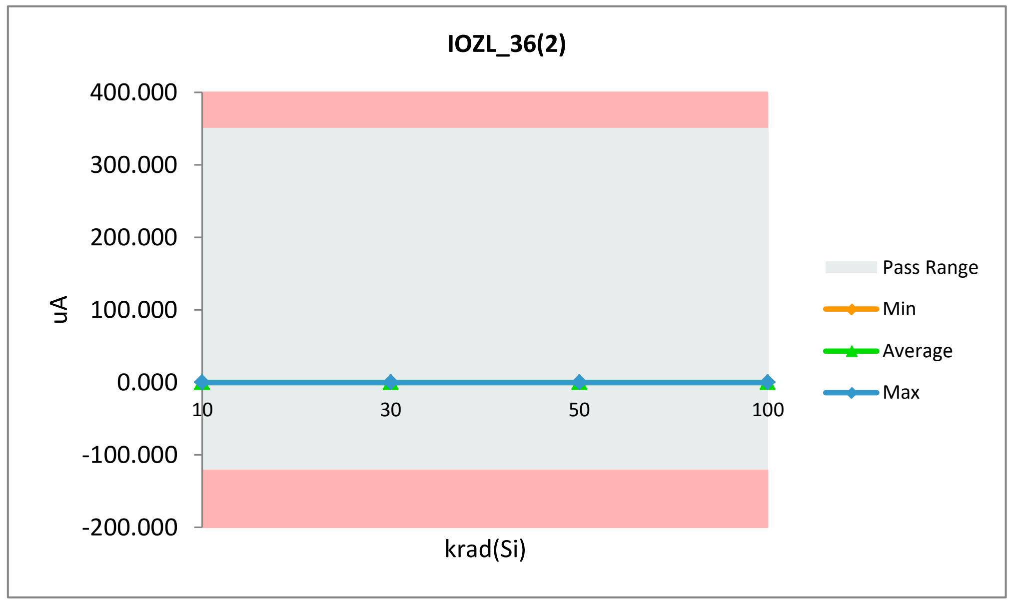
	IOZL_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.096	0.011	-0.107
10	7	-0.022	0.011	-0.033
10	8	-0.096	-0.008	-0.089
10	9	-0.096	-0.008	-0.089
10	10	-0.096	-0.008	-0.089
30	6	-0.096	-0.003	-0.093
30	7	-0.022	-0.022	0.000
30	8	-0.096	-0.022	-0.075
30	9	-0.096	-0.022	-0.075
30	10	-0.096	-0.022	-0.075
50	6	-0.096	-0.010	-0.087
50	7	-0.022	-0.010	-0.012
50	8	-0.096	-0.010	-0.087
50	9	-0.096	-0.010	-0.087
50	10	-0.096	0.009	-0.105
100	B011	-0.022	-0.024	0.002
100	B012	-0.022	-0.024	0.002
100	B013	-0.096	-0.024	-0.072
100	B014	-0.096	-0.024	-0.072
100	B015	-0.096	-0.005	-0.091
	Max	-0.022	0.011	0.002
	Average	-0.078	-0.011	-0.067
	Min	-0.096	-0.024	-0.107
	Std Dev	0.033	0.012	0.036



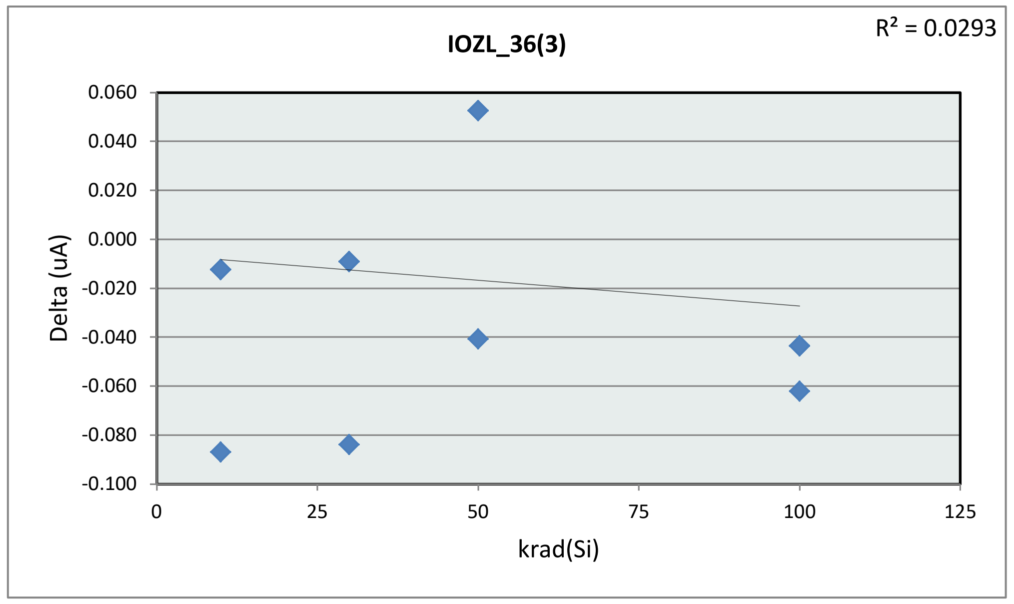
	IOZL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.008	-0.022	-0.010	-0.024
Average	0.000	-0.018	-0.006	-0.020
Max	0.011	-0.003	0.009	-0.005
UL	350.000	350.000	350.000	350.000



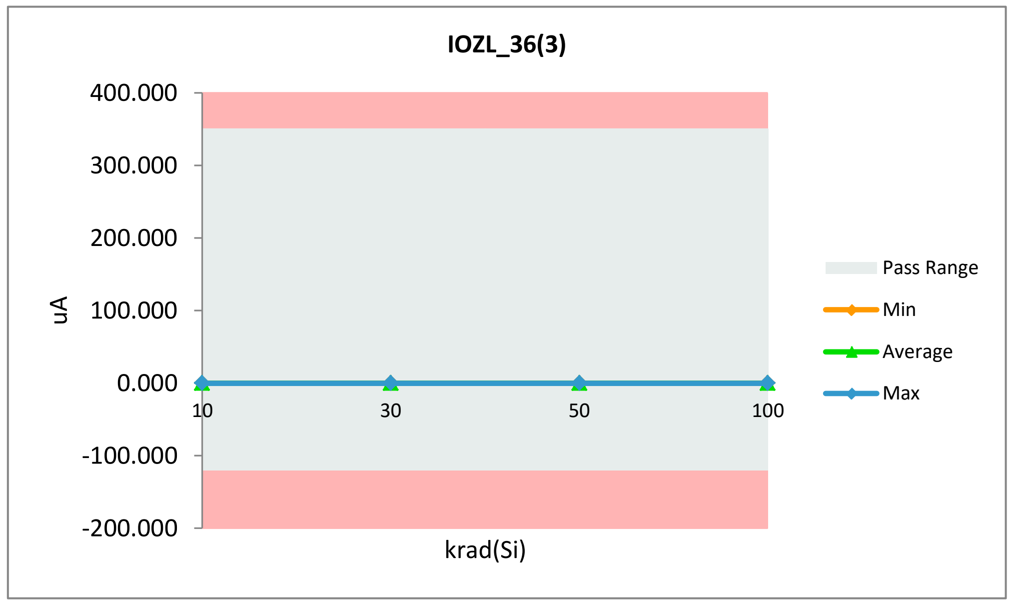
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOZL_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbias	Delta
10	6	-0.015	-0.003	-0.012
10	7	-0.015	-0.003	-0.012
10	8	-0.090	-0.003	-0.087
10	9	-0.015	-0.003	-0.012
10	10	-0.015	-0.003	-0.012
30	6	-0.015	-0.006	-0.009
30	7	-0.015	-0.006	-0.009
30	8	-0.090	-0.006	-0.084
30	9	-0.015	-0.006	-0.009
30	10	-0.015	-0.006	-0.009
50	6	-0.015	-0.068	0.052
50	7	-0.015	-0.068	0.052
50	8	-0.090	-0.049	-0.041
50	9	-0.015	-0.068	0.052
50	10	-0.015	-0.068	0.052
100	B011	-0.015	0.028	-0.044
100	B012	-0.015	0.028	-0.044
100	B013	-0.015	0.028	-0.044
100	B014	-0.015	0.047	-0.062
100	B015	-0.015	0.028	-0.044
	Max	-0.015	0.047	0.052
	Average	-0.027	-0.010	-0.016
	Min	-0.090	-0.068	-0.087
	Std Dev	0.027	0.036	0.043



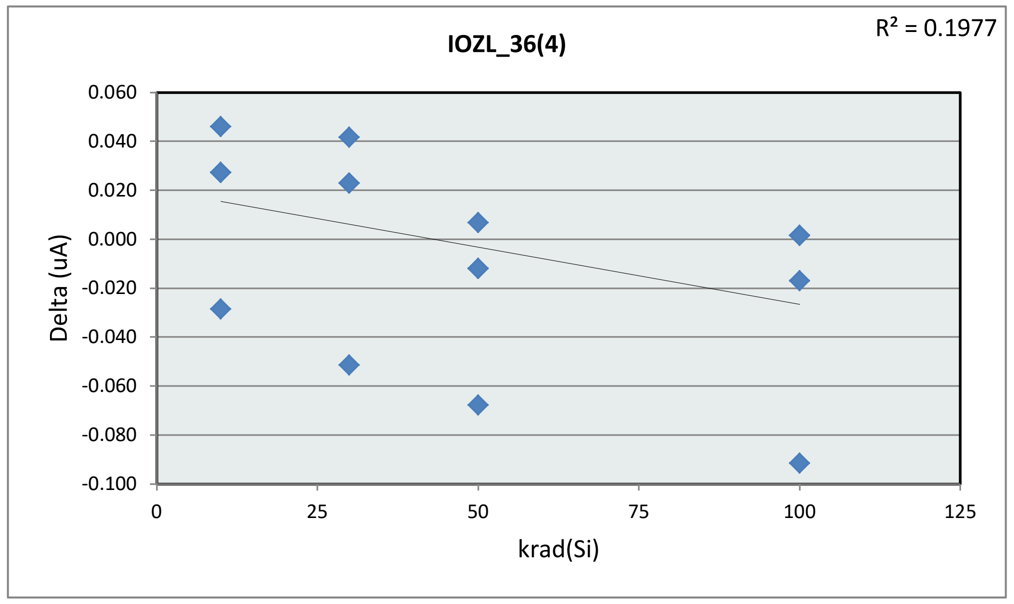
	IOZL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.003	-0.006	-0.068	0.028
Average	-0.003	-0.006	-0.064	0.032
Max	-0.003	-0.006	-0.049	0.047
UL	350.000	350.000	350.000	350.000



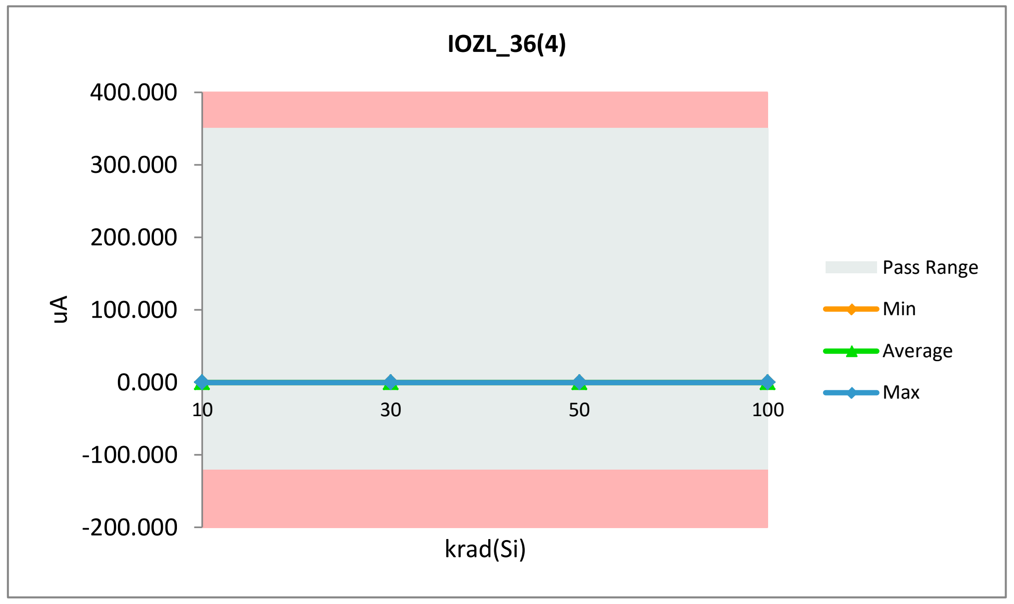
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOZL_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.024	-0.003	0.027
10	7	0.024	-0.003	0.027
10	8	-0.051	-0.022	-0.029
10	9	0.024	-0.003	0.027
10	10	0.024	-0.022	0.046
30	6	0.024	0.001	0.023
30	7	0.024	0.001	0.023
30	8	-0.051	0.001	-0.052
30	9	0.024	-0.018	0.042
30	10	0.024	0.001	0.023
50	6	0.024	0.017	0.007
50	7	0.024	0.036	-0.012
50	8	-0.051	0.017	-0.068
50	9	0.024	0.036	-0.012
50	10	0.024	0.036	-0.012
100	B011	-0.051	0.041	-0.092
100	B012	0.024	0.041	-0.017
100	B013	0.024	0.022	0.001
100	B014	0.024	0.022	0.001
100	B015	0.024	0.022	0.001
	Max	0.024	0.041	0.046
	Average	0.009	0.011	-0.002
	Min	-0.051	-0.022	-0.092
	Std Dev	0.031	0.021	0.036



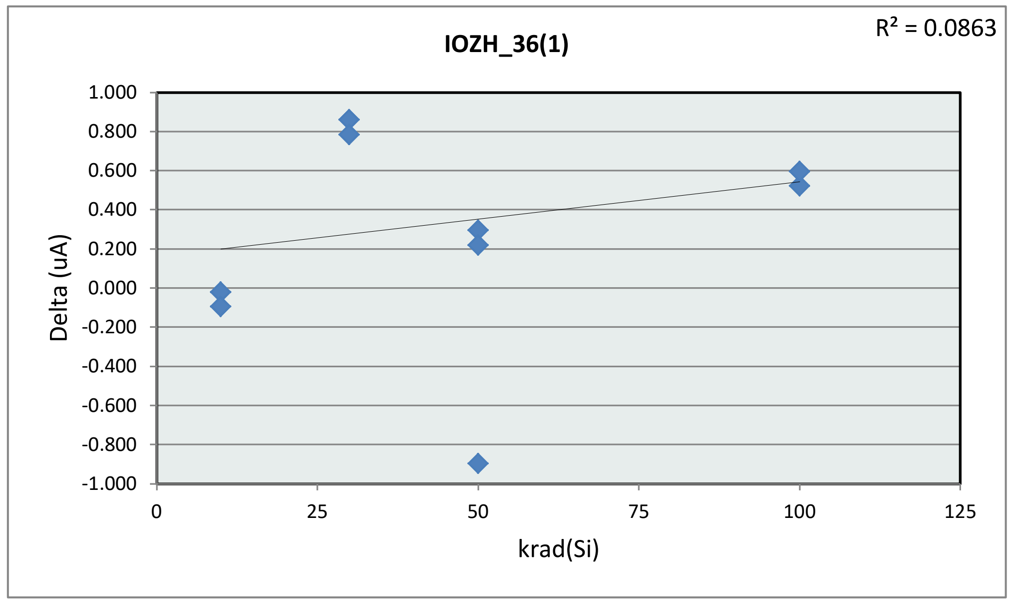
	IOZL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	-0.022	-0.018	0.017	0.022
Average	-0.011	-0.003	0.028	0.030
Max	-0.003	0.001	0.036	0.041
UL	350.000	350.000	350.000	350.000



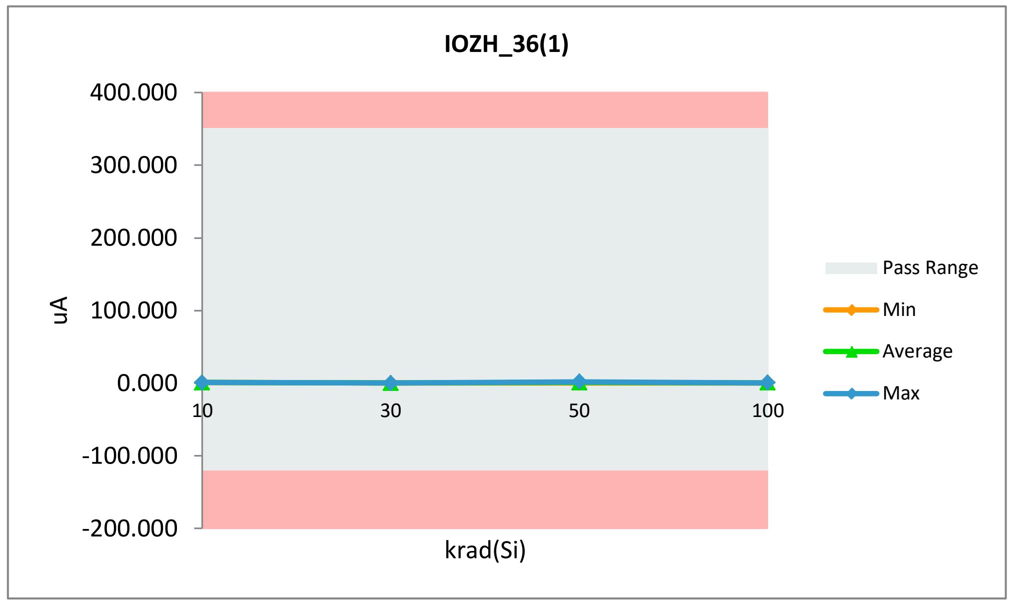
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOZH_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.980	1.001	-0.021
10	7	0.980	1.001	-0.021
10	8	0.980	1.001	-0.021
10	9	0.905	1.001	-0.095
10	10	0.905	1.001	-0.095
30	6	0.980	0.121	0.859
30	7	0.980	0.121	0.859
30	8	0.980	0.121	0.859
30	9	0.905	0.121	0.784
30	10	0.905	0.121	0.784
50	6	0.980	1.877	-0.897
50	7	0.980	0.686	0.294
50	8	0.980	0.686	0.294
50	9	0.905	0.686	0.220
50	10	0.905	0.686	0.220
100	B011	0.905	0.385	0.520
100	B012	0.980	0.385	0.595
100	B013	0.905	0.385	0.520
100	B014	0.980	0.385	0.595
100	B015	0.980	0.385	0.595
	Max	0.980	1.877	0.859
	Average	0.950	0.608	0.342
	Min	0.905	0.121	-0.897
	Std Dev	0.037	0.450	0.447

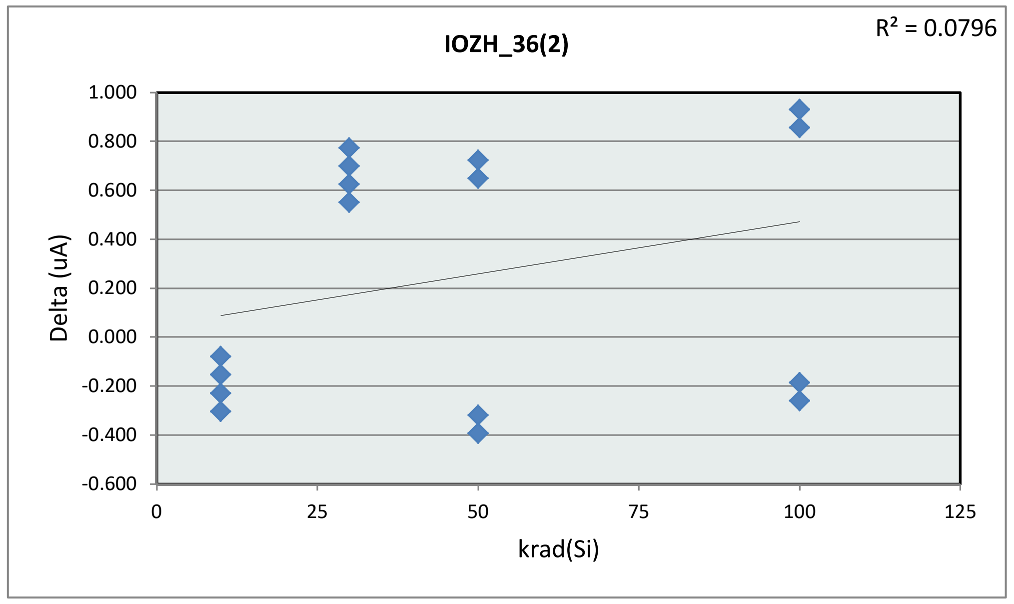


	IOZH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	1.001	0.121	0.686	0.385
Average	1.001	0.121	0.924	0.385
Max	1.001	0.121	1.877	0.385
UL	350.000	350.000	350.000	350.000

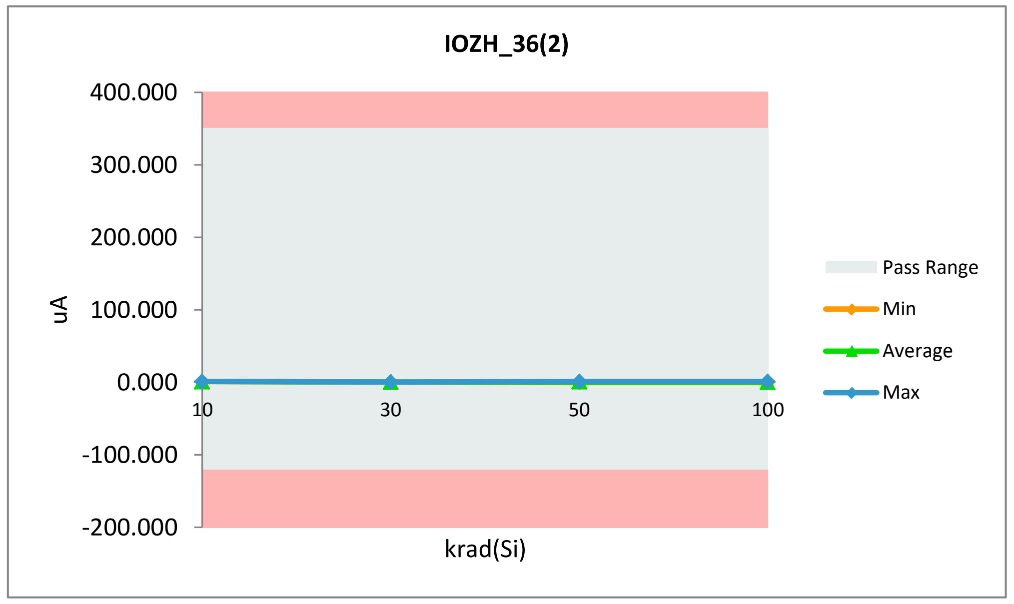


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOZH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	350	350	
	Min Limit	-120	-120	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.021	1.101	-0.080
10	7	0.946	1.101	-0.155
10	8	0.946	1.101	-0.155
10	9	0.797	1.101	-0.304
10	10	0.872	1.101	-0.229
30	6	1.021	0.248	0.773
30	7	0.946	0.248	0.698
30	8	0.946	0.248	0.698
30	9	0.797	0.248	0.549
30	10	0.872	0.248	0.624
50	6	1.021	1.340	-0.319
50	7	0.946	1.340	-0.394
50	8	0.946	1.340	-0.394
50	9	0.797	0.149	0.648
50	10	0.872	0.149	0.722
100	B011	0.946	1.207	-0.261
100	B012	0.946	0.016	0.930
100	B013	0.872	0.016	0.855
100	B014	0.946	0.016	0.930
100	B015	1.021	1.207	-0.186
	Max	1.021	1.340	0.930
	Average	0.924	0.676	0.248
	Min	0.797	0.016	-0.394
	Std Dev	0.073	0.541	0.521

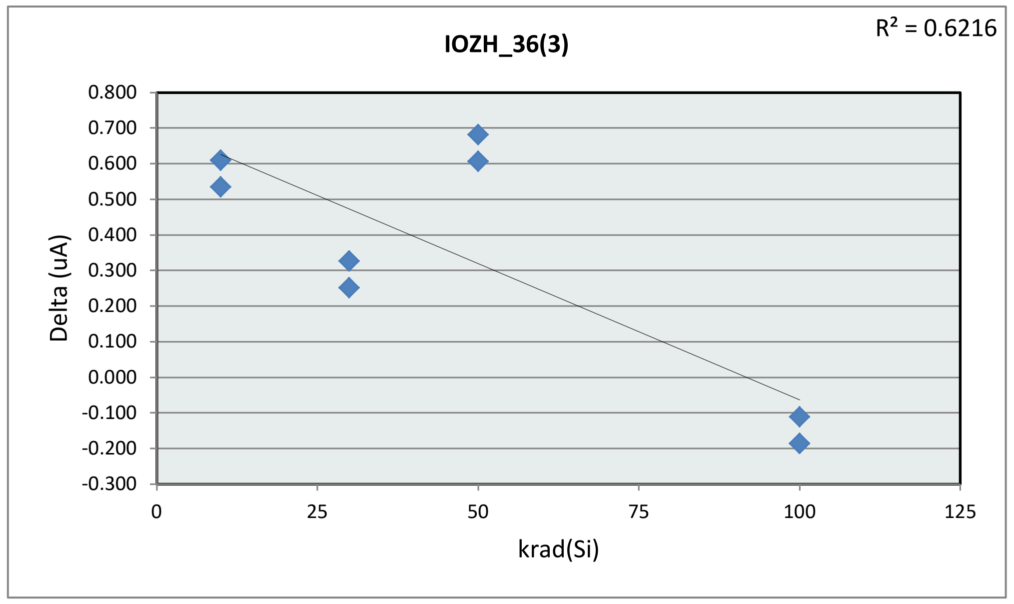


	IOZH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	1.101	0.248	0.149	0.016
Average	1.101	0.248	0.864	0.492
Max	1.101	0.248	1.340	1.207
UL	350.000	350.000	350.000	350.000

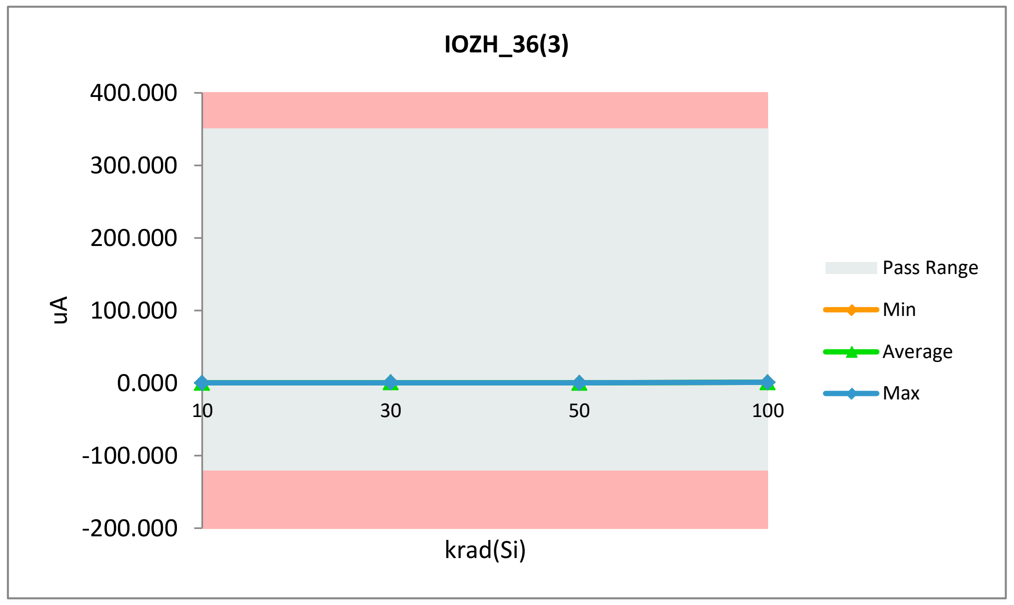


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOZH_36(3)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		350	350	
Min Limit		-120	-120	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.954	0.345	0.609
10	7	0.954	0.345	0.609
10	8	0.954	0.345	0.609
10	9	0.879	0.345	0.535
10	10	0.879	0.345	0.535
30	6	0.954	0.628	0.326
30	7	0.954	0.628	0.326
30	8	0.954	0.628	0.326
30	9	0.879	0.628	0.251
30	10	0.879	0.628	0.251
50	6	0.954	0.273	0.681
50	7	0.954	0.273	0.681
50	8	0.954	0.273	0.681
50	9	0.879	0.273	0.606
50	10	0.879	0.273	0.606
100	B011	0.879	1.066	-0.187
100	B012	0.879	1.066	-0.187
100	B013	0.879	1.066	-0.187
100	B014	0.879	1.066	-0.187
100	B015	0.954	1.066	-0.112
	Max	0.954	1.066	0.681
	Average	0.917	0.578	0.339
	Min	0.879	0.273	-0.187
	Std Dev	0.038	0.320	0.334



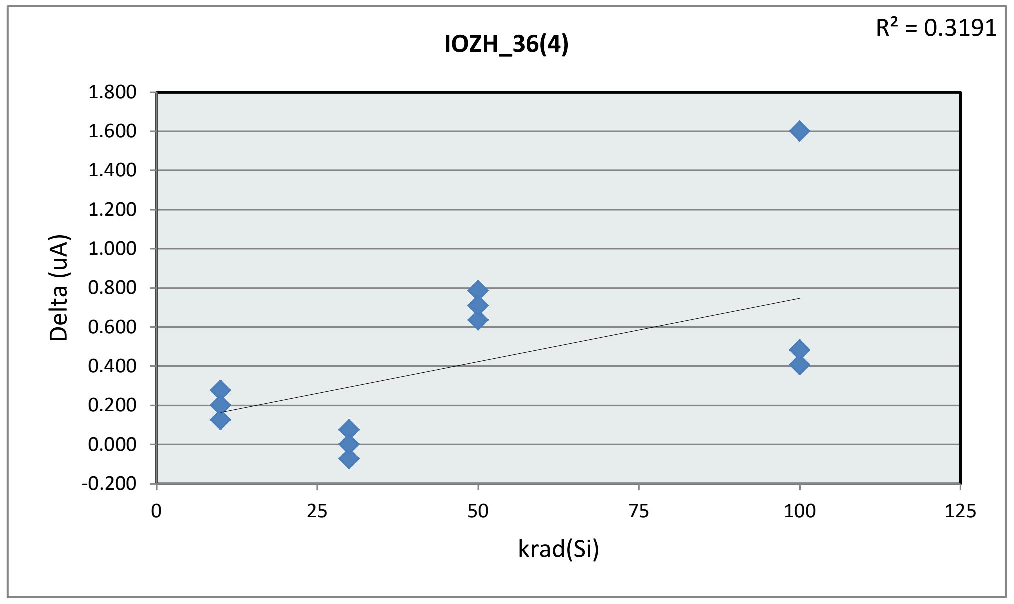
	IOZH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.345	0.628	0.273	1.066
Average	0.345	0.628	0.273	1.066
Max	0.345	0.628	0.273	1.066
UL	350.000	350.000	350.000	350.000



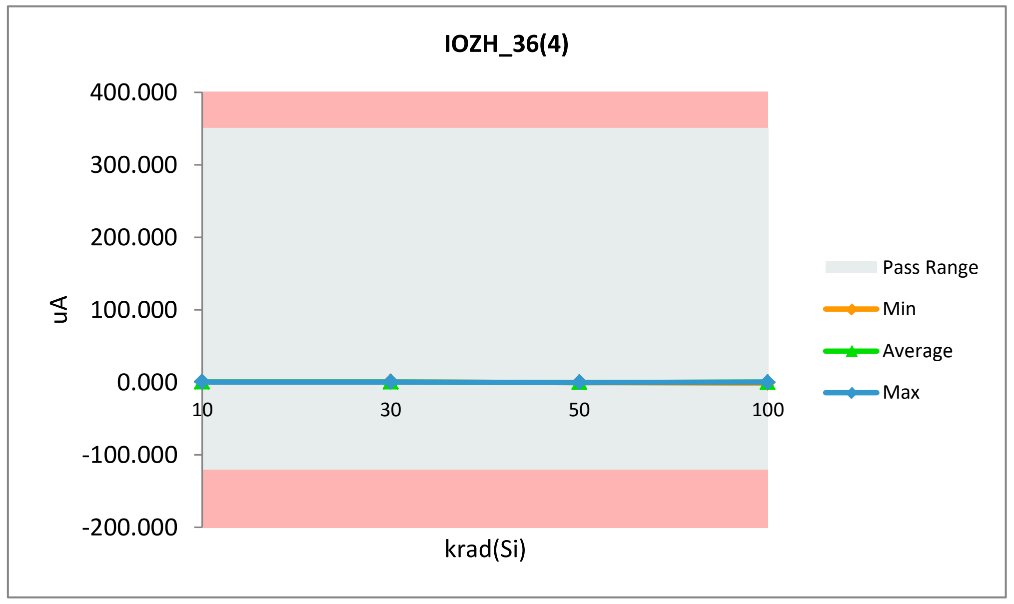
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOZH_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	350	350
Min Limit	-120	-120

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	0.991	0.716	0.275
10	7	0.917	0.716	0.201
10	8	0.991	0.716	0.275
10	9	0.843	0.716	0.126
10	10	0.917	0.716	0.201
30	6	0.991	0.916	0.075
30	7	0.917	0.916	0.001
30	8	0.991	0.916	0.075
30	9	0.843	0.916	-0.074
30	10	0.917	0.916	0.001
50	6	0.991	0.207	0.784
50	7	0.917	0.207	0.710
50	8	0.991	0.207	0.784
50	9	0.843	0.207	0.636
50	10	0.917	0.207	0.710
100	B011	0.917	0.509	0.408
100	B012	0.917	0.509	0.408
100	B013	0.917	-0.682	1.599
100	B014	0.991	0.509	0.482
100	B015	0.991	0.509	0.482
	Max	0.991	0.916	1.599
	Average	0.936	0.528	0.408
	Min	0.843	-0.682	-0.074
	Std Dev	0.053	0.391	0.393

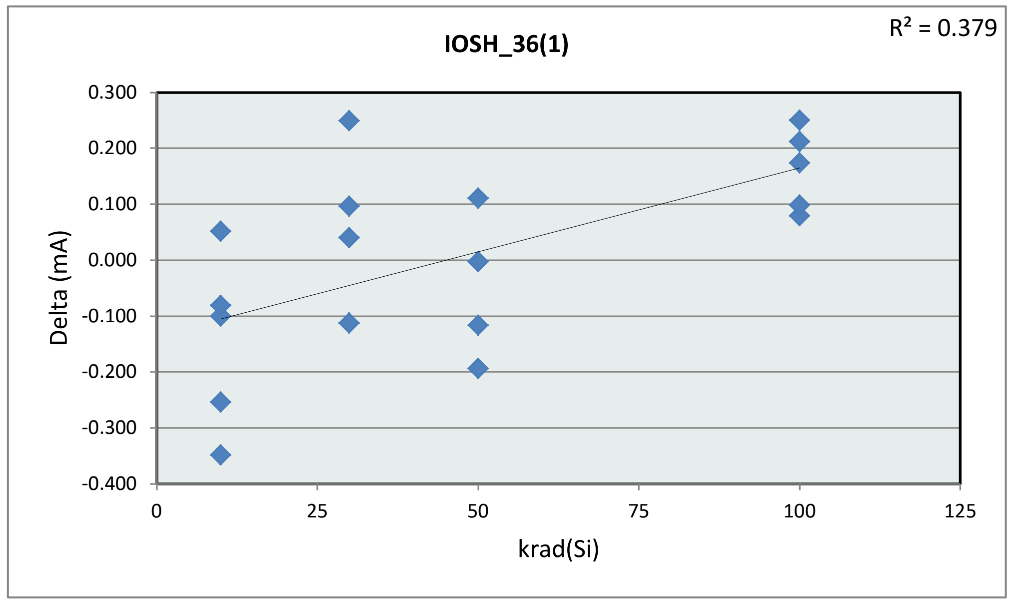


	IOZH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	350	uA		
Min Limit	-120	uA		
krad(Si)	10	30	50	100
LL	-120.000	-120.000	-120.000	-120.000
Min	0.716	0.916	0.207	-0.682
Average	0.716	0.916	0.207	0.271
Max	0.716	0.916	0.207	0.509
UL	350.000	350.000	350.000	350.000

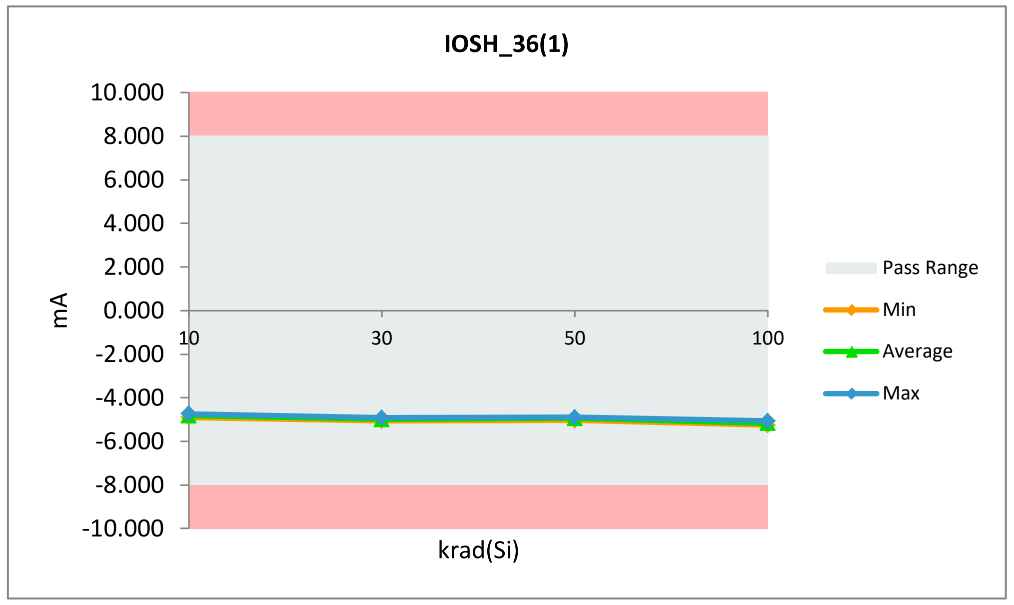


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSH_36(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-5.159	-4.905	-0.254
10	7	-4.892	-4.791	-0.101
10	8	-5.140	-4.791	-0.349
10	9	-4.816	-4.734	-0.082
10	10	-4.816	-4.867	0.051
30	6	-5.159	-5.046	-0.113
30	7	-4.892	-4.932	0.040
30	8	-5.140	-5.027	-0.113
30	9	-4.816	-5.065	0.249
30	10	-4.816	-4.912	0.096
50	6	-5.159	-5.042	-0.117
50	7	-4.892	-4.889	-0.003
50	8	-5.140	-4.946	-0.194
50	9	-4.816	-4.927	0.111
50	10	-4.816	-4.927	0.111
100	B011	-4.892	-5.066	0.174
100	B012	-4.949	-5.199	0.250
100	B013	-4.930	-5.142	0.212
100	B014	-5.159	-5.238	0.079
100	B015	-5.159	-5.257	0.098
	Max	-4.816	-4.734	0.250
	Average	-4.978	-4.985	0.007
	Min	-5.159	-5.257	-0.349
	Std Dev	0.151	0.148	0.167

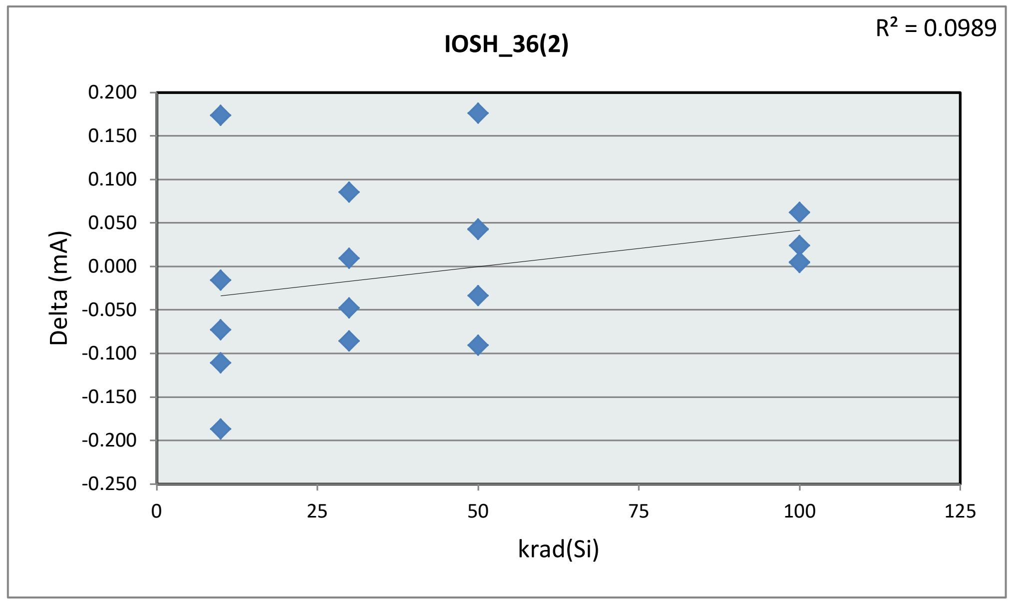


	IOSH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.905	-5.065	-5.042	-5.257
Average	-4.818	-4.996	-4.946	-5.180
Max	-4.734	-4.912	-4.889	-5.066
UL	8.000	8.000	8.000	8.000

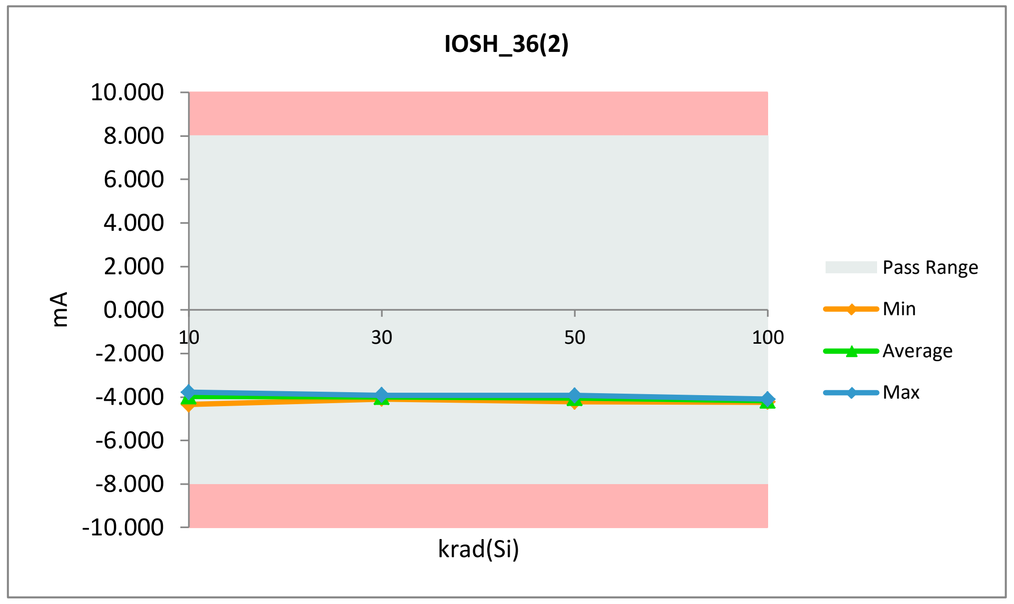


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSH_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-4.177	-4.351	0.174
10	7	-3.949	-3.838	-0.111
10	8	-4.101	-4.085	-0.016
10	9	-3.968	-3.781	-0.187
10	10	-3.949	-3.876	-0.073
30	6	-4.177	-4.091	-0.086
30	7	-3.949	-3.958	0.009
30	8	-4.101	-4.015	-0.086
30	9	-3.968	-3.920	-0.048
30	10	-3.949	-4.034	0.085
50	6	-4.177	-4.220	0.043
50	7	-3.949	-3.991	0.042
50	8	-4.101	-4.010	-0.091
50	9	-3.968	-3.934	-0.034
50	10	-3.949	-4.125	0.176
100	B011	-4.101	-4.163	0.062
100	B012	-4.177	-4.239	0.062
100	B013	-4.158	-4.182	0.024
100	B014	-4.101	-4.105	0.004
100	B015	-4.177	-4.182	0.005
	Max	-3.949	-3.781	0.176
	Average	-4.057	-4.055	-0.002
	Min	-4.177	-4.351	-0.187
	Std Dev	0.099	0.146	0.092



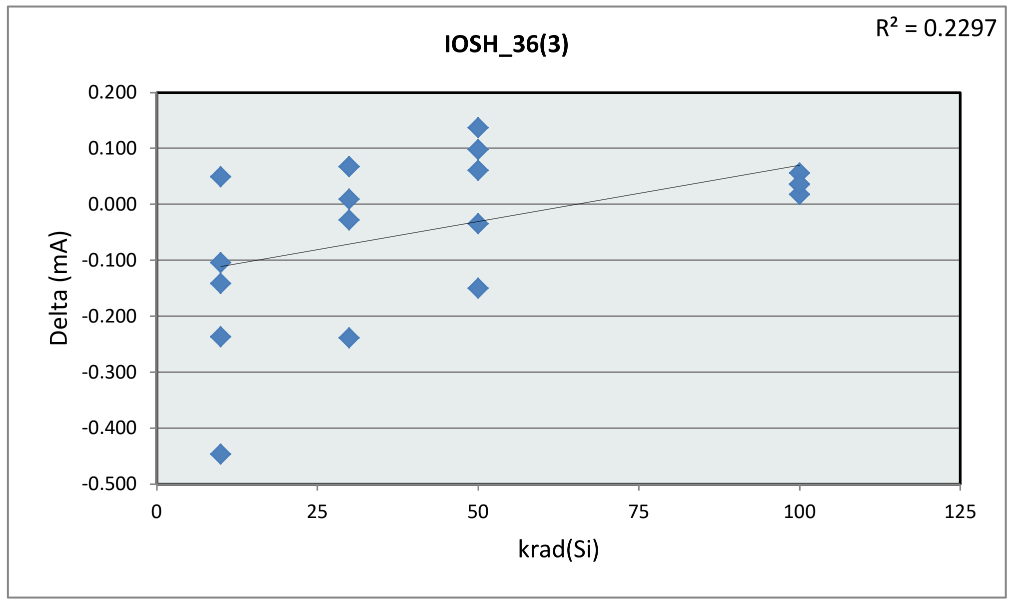
	IOSH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.351	-4.091	-4.220	-4.239
Average	-3.986	-4.004	-4.056	-4.174
Max	-3.781	-3.920	-3.934	-4.105
UL	8.000	8.000	8.000	8.000



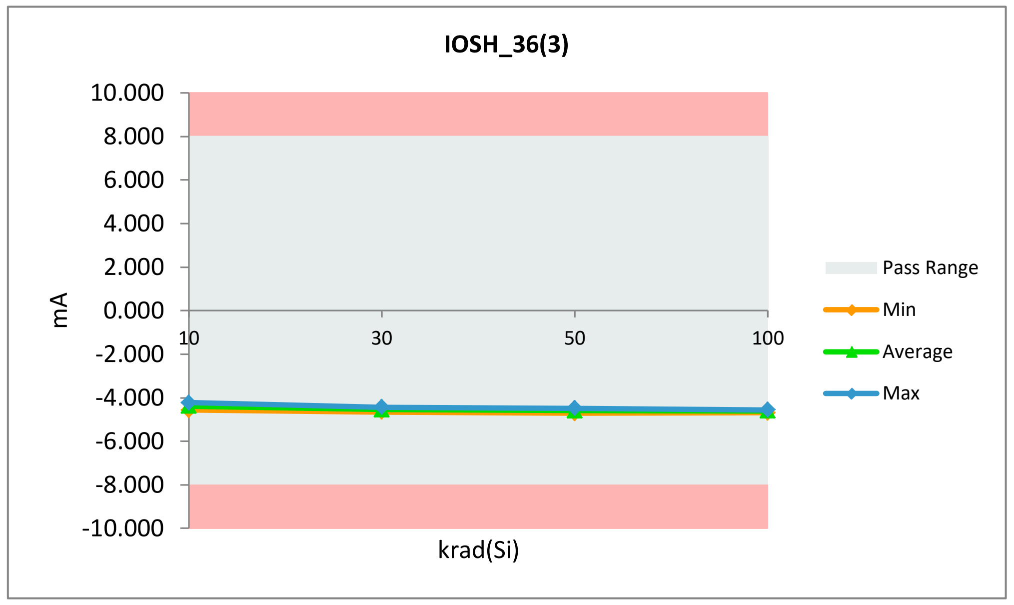
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOSH_36(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-4.651	-4.547	-0.104
10	7	-4.479	-4.337	-0.142
10	8	-4.670	-4.223	-0.447
10	9	-4.517	-4.280	-0.237
10	10	-4.517	-4.566	0.049
30	6	-4.651	-4.660	0.009
30	7	-4.479	-4.546	0.067
30	8	-4.670	-4.431	-0.239
30	9	-4.517	-4.489	-0.028
30	10	-4.517	-4.584	0.067
50	6	-4.651	-4.711	0.060
50	7	-4.479	-4.577	0.098
50	8	-4.670	-4.520	-0.150
50	9	-4.517	-4.482	-0.035
50	10	-4.517	-4.654	0.137
100	B011	-4.556	-4.592	0.036
100	B012	-4.594	-4.611	0.017
100	B013	-4.498	-4.554	0.056
100	B014	-4.575	-4.611	0.036
100	B015	-4.651	-4.687	0.036
	Max	-4.479	-4.223	0.137
	Average	-4.569	-4.533	-0.036
	Min	-4.670	-4.711	-0.447
	Std Dev	0.074	0.130	0.144

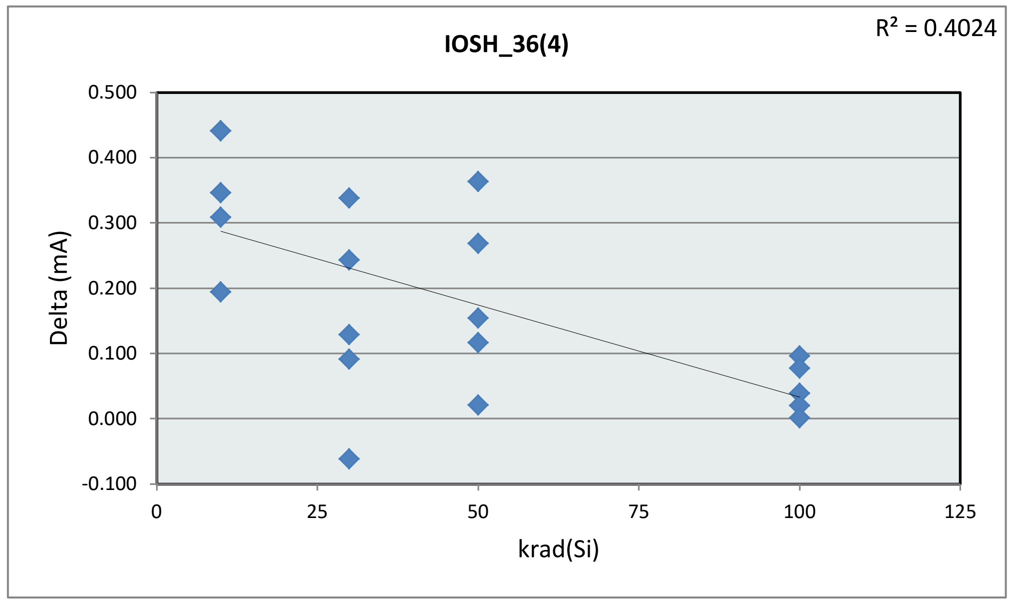


	IOSH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.566	-4.660	-4.711	-4.687
Average	-4.391	-4.542	-4.589	-4.611
Max	-4.223	-4.431	-4.482	-4.554
UL	8.000	8.000	8.000	8.000

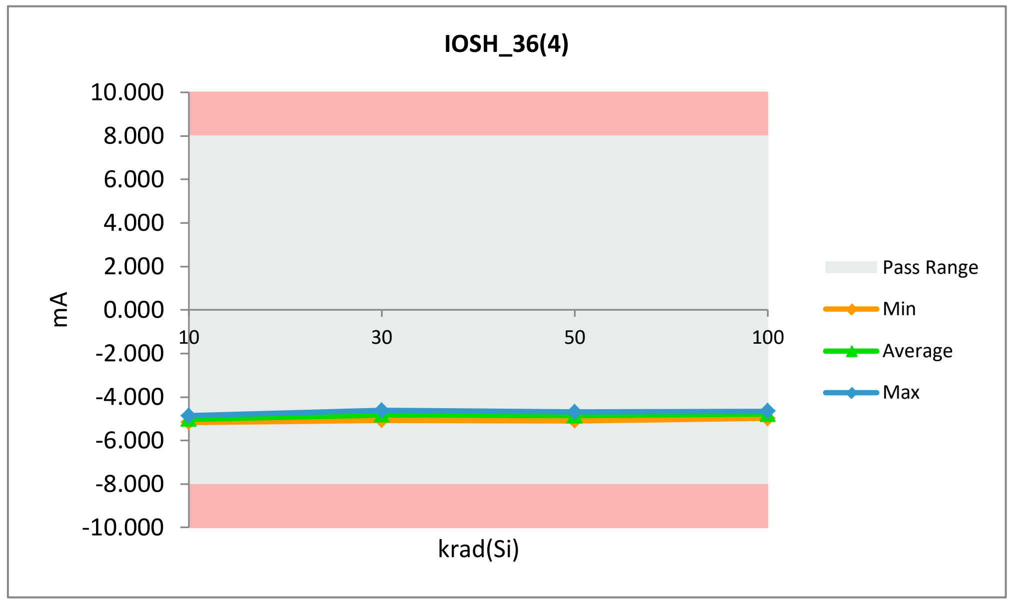


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSH_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-4.731	-5.172	0.441
10	7	-4.598	-5.039	0.441
10	8	-4.674	-4.868	0.194
10	9	-4.674	-4.982	0.308
10	10	-4.731	-5.077	0.346
30	6	-4.731	-5.069	0.338
30	7	-4.598	-4.727	0.129
30	8	-4.674	-4.765	0.091
30	9	-4.674	-4.612	-0.062
30	10	-4.731	-4.974	0.243
50	6	-4.731	-5.094	0.363
50	7	-4.598	-4.752	0.154
50	8	-4.674	-4.790	0.116
50	9	-4.674	-4.695	0.021
50	10	-4.731	-4.999	0.268
100	B011	-4.940	-4.979	0.039
100	B012	-4.807	-4.827	0.020
100	B013	-4.560	-4.656	0.096
100	B014	-4.693	-4.694	0.001
100	B015	-4.731	-4.808	0.077
	Max	-4.560	-4.612	0.441
	Average	-4.698	-4.879	0.181
	Min	-4.940	-5.172	-0.062
	Std Dev	0.083	0.168	0.153

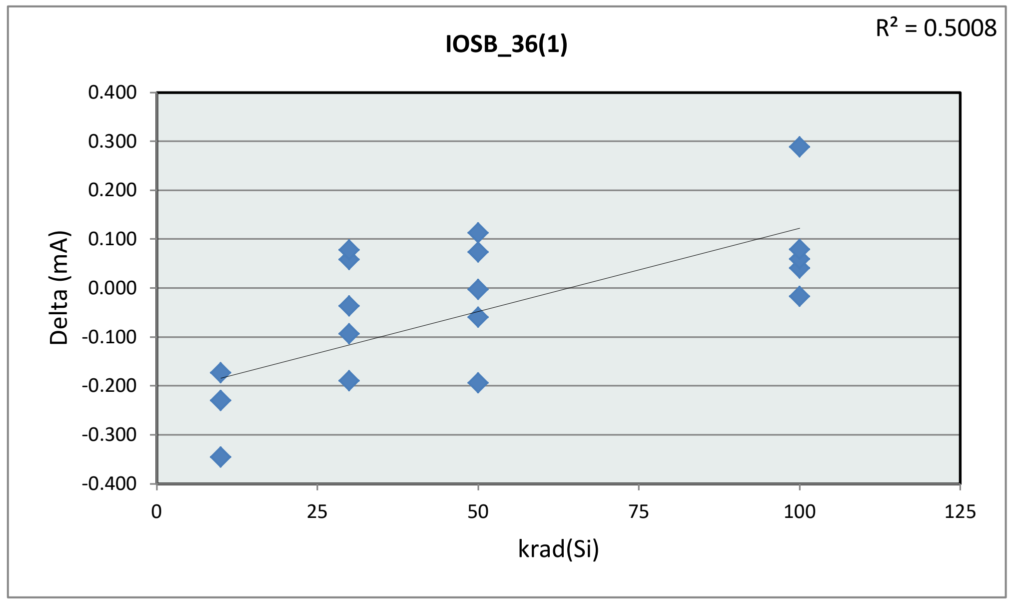


	IOSH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.172	-5.069	-5.094	-4.979
Average	-5.028	-4.829	-4.866	-4.793
Max	-4.868	-4.612	-4.695	-4.656
UL	8.000	8.000	8.000	8.000

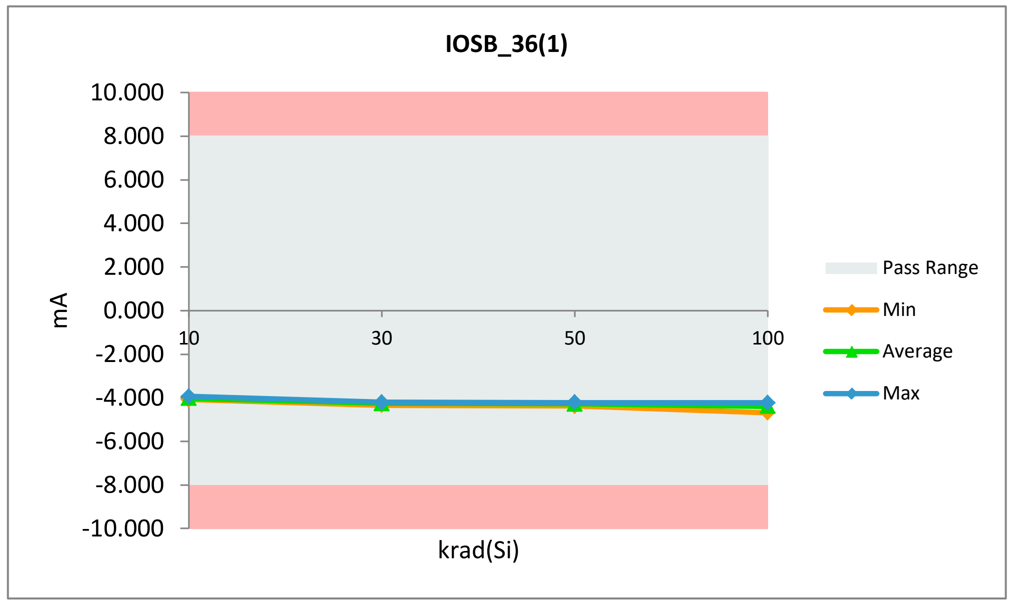


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-4.435	-4.090	-0.345
10	7	-4.244	-4.071	-0.173
10	8	-4.416	-4.071	-0.345
10	9	-4.168	-3.938	-0.230
10	10	-4.206	-3.976	-0.230
30	6	-4.435	-4.341	-0.094
30	7	-4.244	-4.207	-0.037
30	8	-4.416	-4.226	-0.190
30	9	-4.168	-4.226	0.058
30	10	-4.206	-4.284	0.078
50	6	-4.435	-4.375	-0.060
50	7	-4.244	-4.241	-0.003
50	8	-4.416	-4.222	-0.194
50	9	-4.168	-4.241	0.073
50	10	-4.206	-4.318	0.112
100	B011	-4.244	-4.285	0.041
100	B012	-4.168	-4.227	0.059
100	B013	-4.244	-4.323	0.079
100	B014	-4.397	-4.685	0.288
100	B015	-4.435	-4.418	-0.017
	Max	-4.168	-3.938	0.288
	Average	-4.295	-4.238	-0.057
	Min	-4.435	-4.685	-0.345
	Std Dev	0.111	0.165	0.165

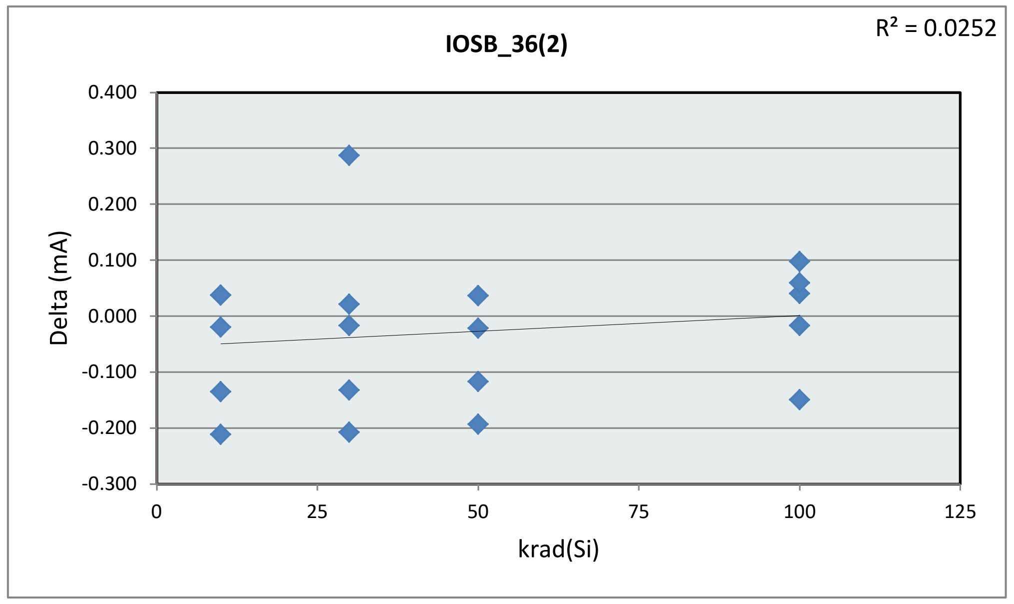


	IOSB_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.090	-4.341	-4.375	-4.685
Average	-4.029	-4.257	-4.279	-4.388
Max	-3.938	-4.207	-4.222	-4.227
UL	8.000	8.000	8.000	8.000

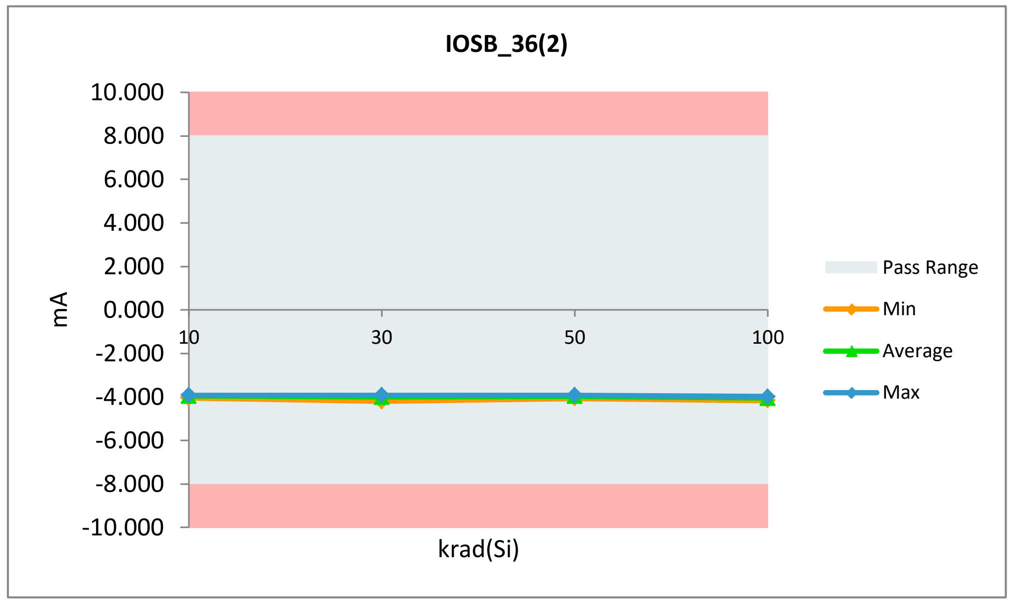


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-4.263	-4.052	-0.211
10	7	-3.939	-3.919	-0.020
10	8	-4.054	-3.919	-0.135
10	9	-3.901	-3.938	0.037
10	10	-3.920	-3.957	0.037
30	6	-4.263	-4.055	-0.208
30	7	-3.939	-3.922	-0.017
30	8	-4.054	-3.922	-0.132
30	9	-3.901	-3.922	0.021
30	10	-3.920	-4.207	0.287
50	6	-4.263	-4.070	-0.193
50	7	-3.939	-3.917	-0.022
50	8	-4.054	-3.937	-0.117
50	9	-3.901	-3.937	0.036
50	10	-3.920	-3.956	0.036
100	B011	-3.997	-3.980	-0.017
100	B012	-3.978	-4.018	0.040
100	B013	-3.959	-4.018	0.059
100	B014	-4.073	-4.170	0.097
100	B015	-4.263	-4.113	-0.150
	Max	-3.901	-3.917	0.287
	Average	-4.025	-3.996	-0.029
	Min	-4.263	-4.207	-0.211
	Std Dev	0.134	0.089	0.122

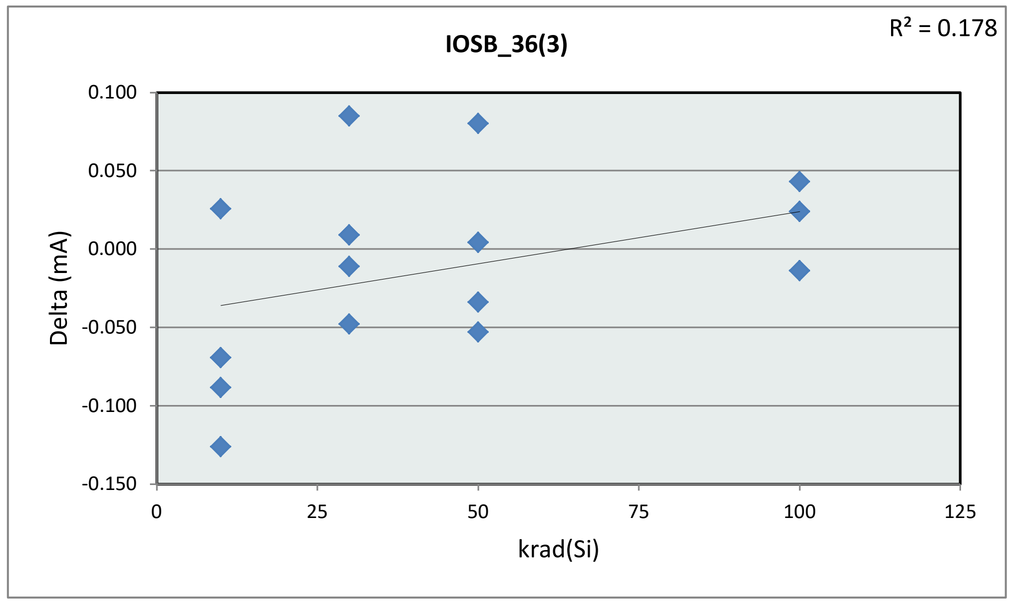


	IOSB_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.052	-4.207	-4.070	-4.170
Average	-3.957	-4.006	-3.963	-4.060
Max	-3.919	-3.922	-3.917	-3.980
UL	8.000	8.000	8.000	8.000

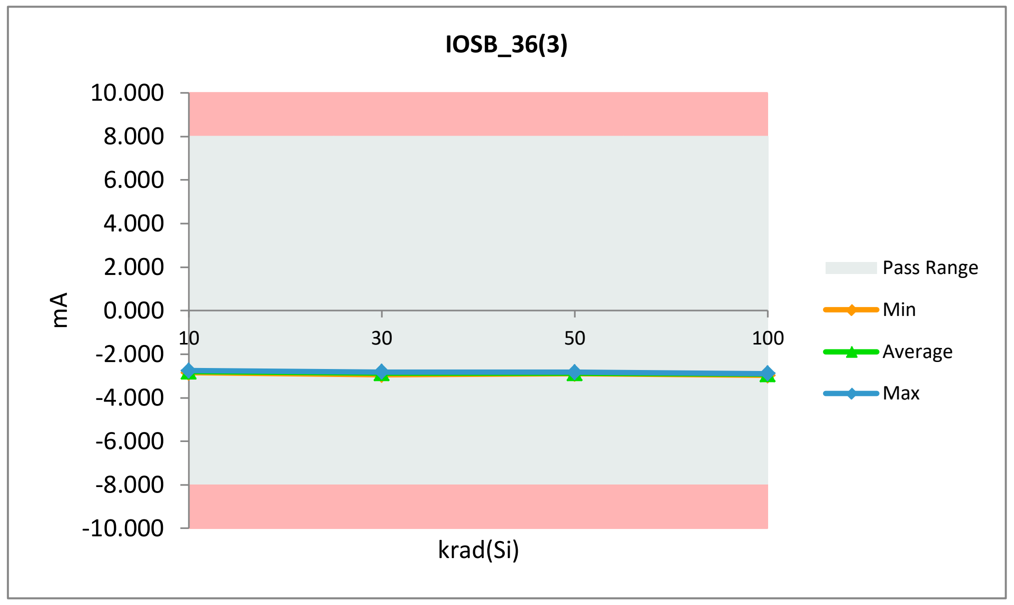


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-2.939	-2.813	-0.126
10	7	-2.863	-2.794	-0.069
10	8	-2.939	-2.851	-0.088
10	9	-2.825	-2.756	-0.069
10	10	-2.806	-2.832	0.026
30	6	-2.939	-2.891	-0.048
30	7	-2.863	-2.872	0.009
30	8	-2.939	-2.948	0.009
30	9	-2.825	-2.814	-0.011
30	10	-2.806	-2.891	0.085
50	6	-2.939	-2.886	-0.053
50	7	-2.863	-2.867	0.004
50	8	-2.939	-2.905	-0.034
50	9	-2.825	-2.829	0.004
50	10	-2.806	-2.886	0.080
100	B011	-2.863	-2.887	0.024
100	B012	-2.920	-2.906	-0.014
100	B013	-2.901	-2.925	0.024
100	B014	-2.939	-2.925	-0.014
100	B015	-2.939	-2.982	0.043
	Max	-2.806	-2.756	0.085
	Average	-2.884	-2.873	-0.011
	Min	-2.939	-2.982	-0.126
	Std Dev	0.054	0.055	0.054



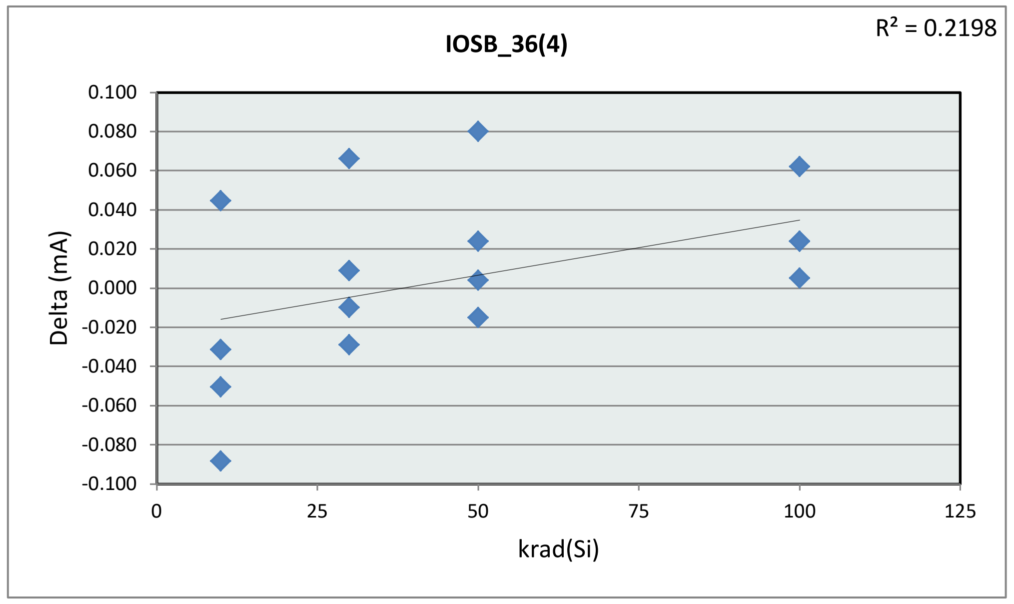
	IOSB_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.851	-2.948	-2.905	-2.982
Average	-2.809	-2.883	-2.875	-2.925
Max	-2.756	-2.814	-2.829	-2.887
UL	8.000	8.000	8.000	8.000



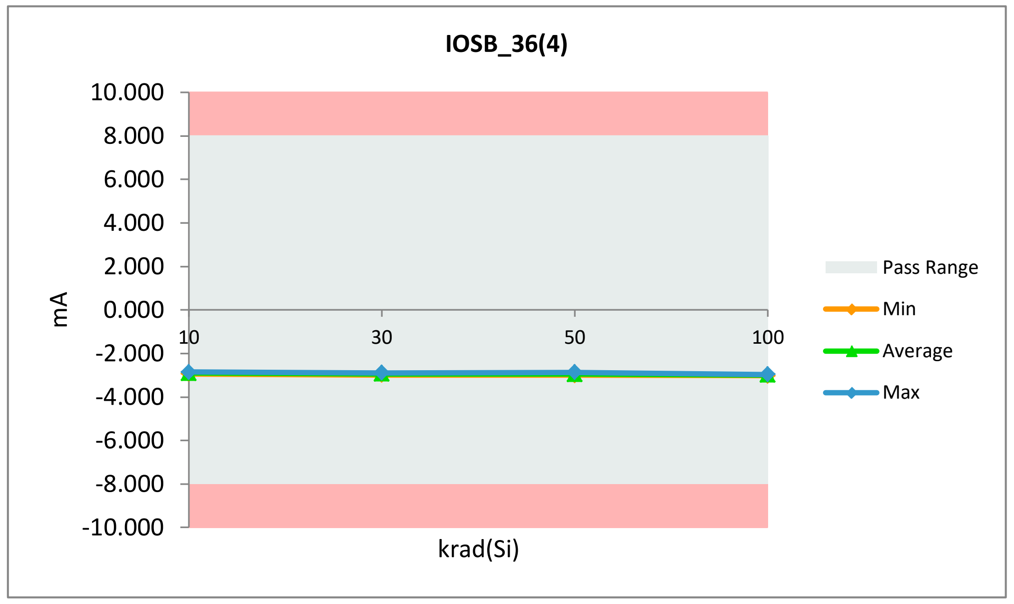
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOSB_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-2.996	-2.908	-0.088
10	7	-2.920	-2.870	-0.050
10	8	-2.977	-2.946	-0.031
10	9	-2.882	-2.851	-0.031
10	10	-2.882	-2.927	0.045
30	6	-2.996	-2.967	-0.029
30	7	-2.920	-2.910	-0.010
30	8	-2.977	-2.986	0.009
30	9	-2.882	-2.891	0.009
30	10	-2.882	-2.948	0.066
50	6	-2.996	-2.981	-0.015
50	7	-2.920	-2.924	0.004
50	8	-2.977	-3.001	0.024
50	9	-2.882	-2.867	-0.015
50	10	-2.882	-2.962	0.080
100	B011	-2.939	-2.963	0.024
100	B012	-2.958	-3.020	0.062
100	B013	-2.958	-2.963	0.005
100	B014	-2.977	-3.001	0.024
100	B015	-2.996	-3.020	0.024
	Max	-2.882	-2.851	0.080
	Average	-2.940	-2.945	0.005
	Min	-2.996	-3.020	-0.088
	Std Dev	0.046	0.051	0.041

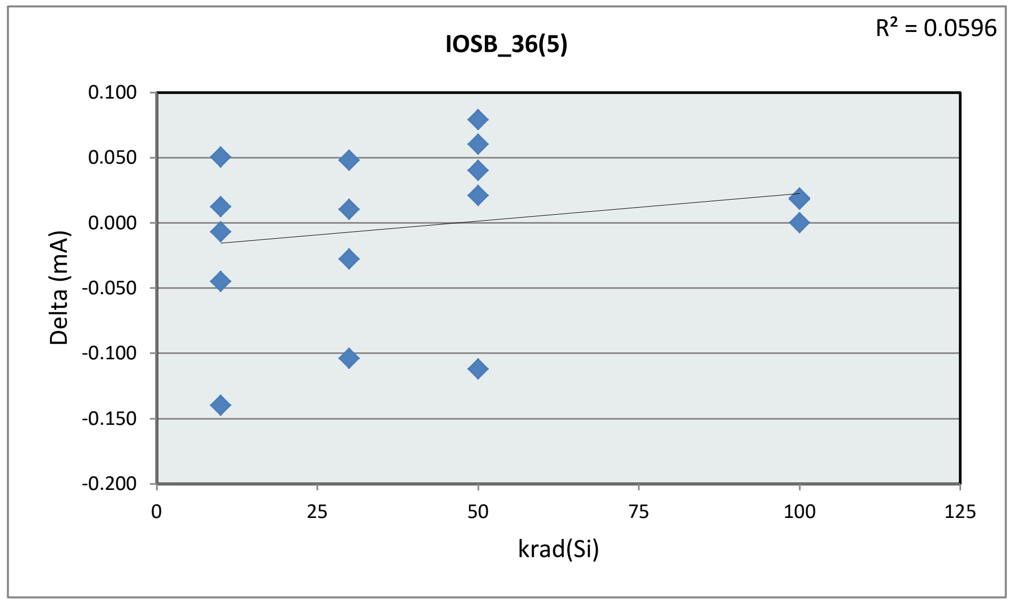


	IOSB_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-2.946	-2.986	-3.001	-3.020
Average	-2.900	-2.940	-2.947	-2.993
Max	-2.851	-2.891	-2.867	-2.963
UL	8.000	8.000	8.000	8.000

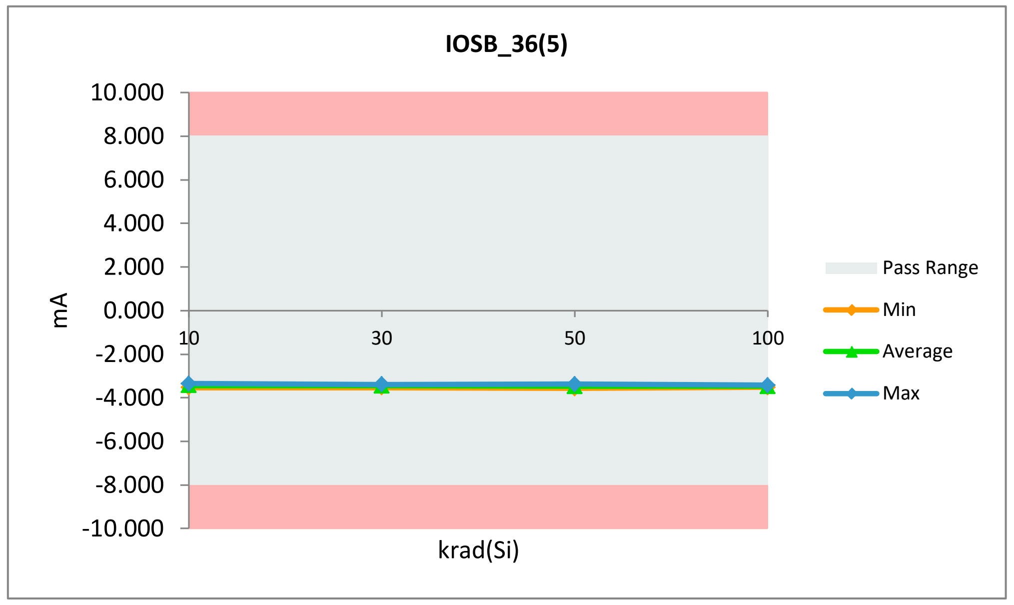


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-3.487	-3.537	0.050
10	7	-3.430	-3.423	-0.007
10	8	-3.487	-3.347	-0.140
10	9	-3.449	-3.404	-0.045
10	10	-3.449	-3.461	0.012
30	6	-3.487	-3.535	0.048
30	7	-3.430	-3.440	0.010
30	8	-3.487	-3.383	-0.104
30	9	-3.449	-3.421	-0.028
30	10	-3.449	-3.497	0.048
50	6	-3.487	-3.566	0.079
50	7	-3.430	-3.470	0.040
50	8	-3.487	-3.375	-0.112
50	9	-3.449	-3.470	0.021
50	10	-3.449	-3.509	0.060
100	B011	-3.487	-3.506	0.019
100	B012	-3.525	-3.525	0.000
100	B013	-3.411	-3.429	0.018
100	B014	-3.411	-3.429	0.018
100	B015	-3.487	-3.506	0.019
	Max	-3.411	-3.347	0.079
	Average	-3.461	-3.462	0.000
	Min	-3.525	-3.566	-0.140
	Std Dev	0.031	0.060	0.059

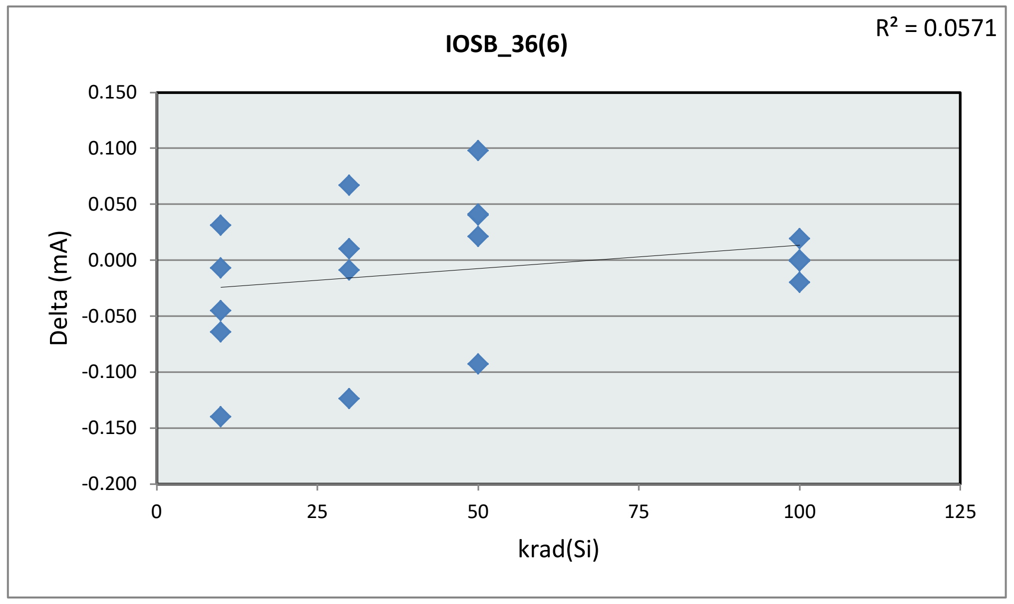


	IOSB_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.537	-3.535	-3.566	-3.525
Average	-3.435	-3.455	-3.478	-3.479
Max	-3.347	-3.383	-3.375	-3.429
UL	8.000	8.000	8.000	8.000

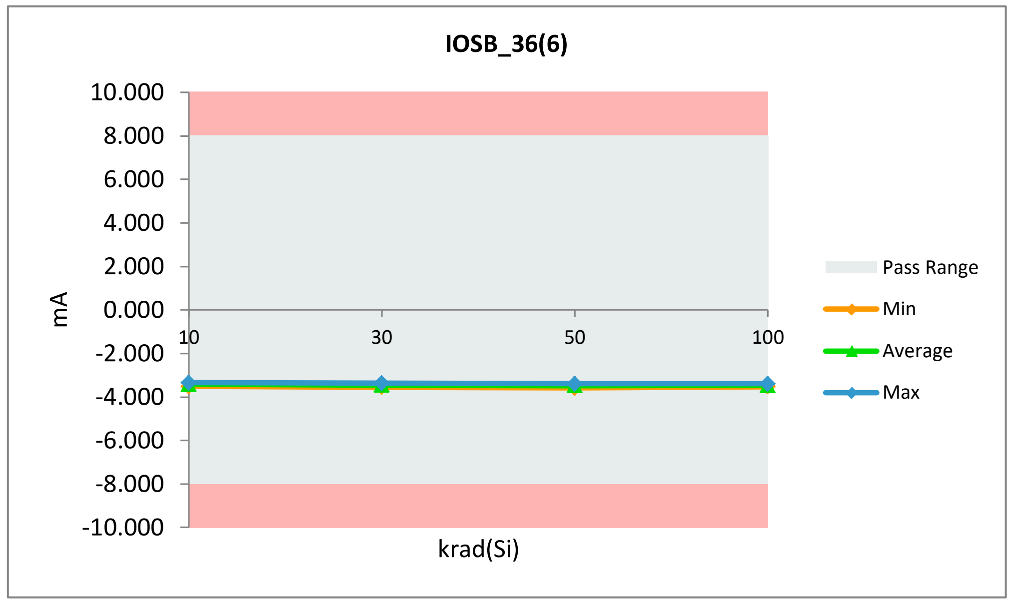


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-3.487	-3.518	0.031
10	7	-3.430	-3.385	-0.045
10	8	-3.487	-3.347	-0.140
10	9	-3.430	-3.366	-0.064
10	10	-3.468	-3.461	-0.007
30	6	-3.487	-3.554	0.067
30	7	-3.430	-3.440	0.010
30	8	-3.487	-3.363	-0.124
30	9	-3.430	-3.421	-0.009
30	10	-3.468	-3.478	0.010
50	6	-3.487	-3.585	0.098
50	7	-3.430	-3.470	0.040
50	8	-3.487	-3.394	-0.093
50	9	-3.430	-3.451	0.021
50	10	-3.468	-3.509	0.041
100	B011	-3.506	-3.506	0.000
100	B012	-3.506	-3.525	0.019
100	B013	-3.411	-3.391	-0.020
100	B014	-3.430	-3.429	-0.001
100	B015	-3.487	-3.486	-0.001
	Max	-3.411	-3.347	0.098
	Average	-3.462	-3.454	-0.008
	Min	-3.506	-3.585	-0.140
	Std Dev	0.031	0.067	0.060



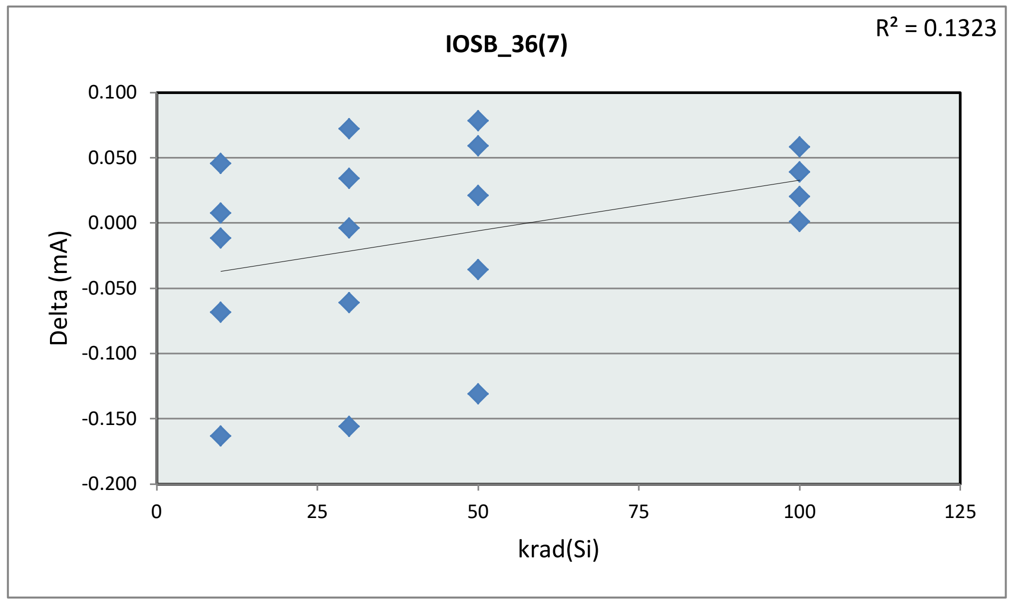
	IOSB_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.518	-3.554	-3.585	-3.525
Average	-3.415	-3.451	-3.482	-3.467
Max	-3.347	-3.363	-3.394	-3.391
UL	8.000	8.000	8.000	8.000



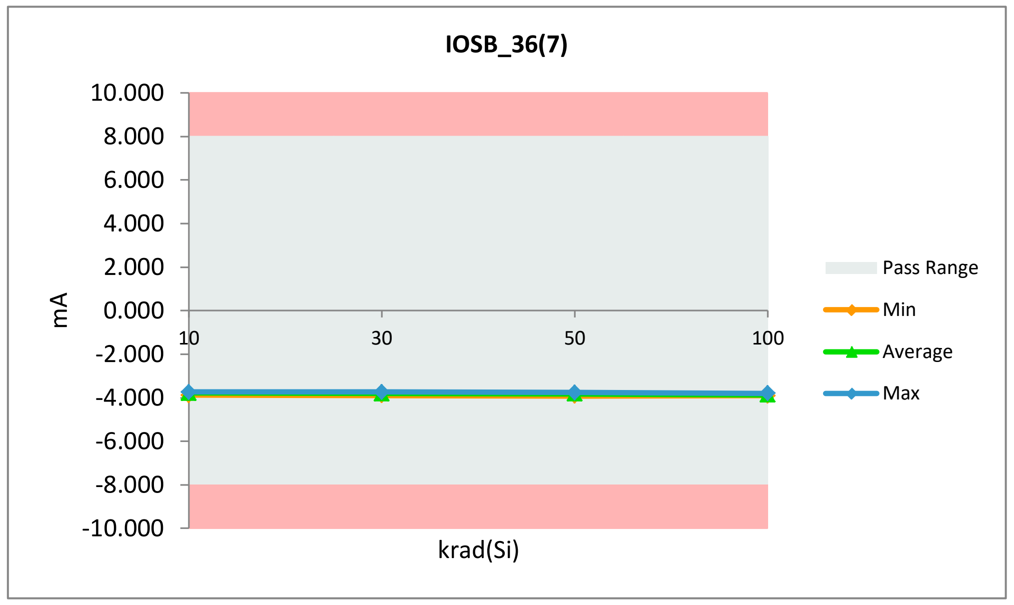
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOSB_36(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-3.893	-3.881	-0.012
10	7	-3.741	-3.786	0.045
10	8	-3.893	-3.730	-0.163
10	9	-3.817	-3.748	-0.069
10	10	-3.798	-3.805	0.007
30	6	-3.893	-3.889	-0.004
30	7	-3.741	-3.813	0.072
30	8	-3.893	-3.737	-0.156
30	9	-3.817	-3.756	-0.061
30	10	-3.798	-3.832	0.034
50	6	-3.893	-3.914	0.021
50	7	-3.741	-3.819	0.078
50	8	-3.893	-3.762	-0.131
50	9	-3.817	-3.781	-0.036
50	10	-3.798	-3.857	0.059
100	B011	-3.817	-3.856	0.039
100	B012	-3.874	-3.913	0.039
100	B013	-3.779	-3.799	0.020
100	B014	-3.817	-3.875	0.058
100	B015	-3.893	-3.894	0.001
	Max	-3.741	-3.730	0.078
	Average	-3.830	-3.822	-0.008
	Min	-3.893	-3.914	-0.163
	Std Dev	0.056	0.060	0.073

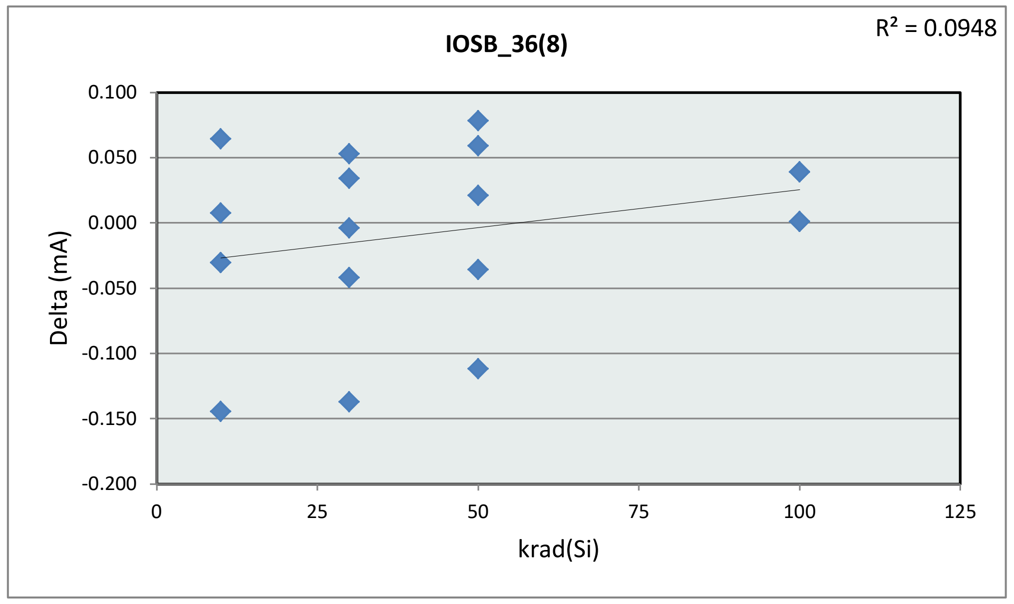


	IOSB_36(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.881	-3.889	-3.914	-3.913
Average	-3.790	-3.805	-3.827	-3.867
Max	-3.730	-3.737	-3.762	-3.799
UL	8.000	8.000	8.000	8.000

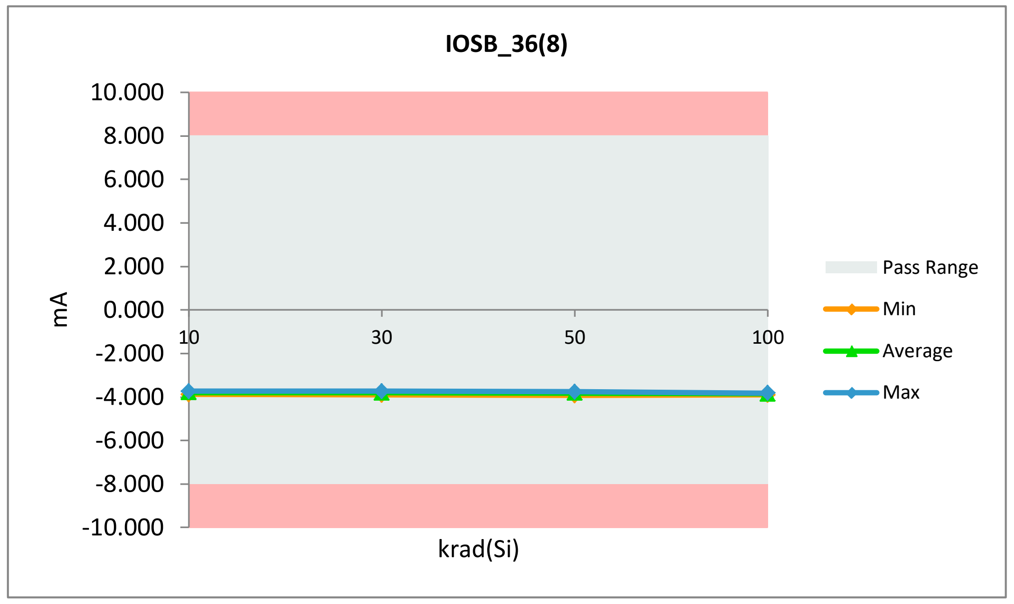


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSB_36(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-3.874	-3.881	0.007
10	7	-3.760	-3.824	0.064
10	8	-3.874	-3.730	-0.144
10	9	-3.798	-3.767	-0.031
10	10	-3.817	-3.786	-0.031
30	6	-3.874	-3.908	0.034
30	7	-3.760	-3.813	0.053
30	8	-3.874	-3.737	-0.137
30	9	-3.798	-3.756	-0.042
30	10	-3.817	-3.813	-0.004
50	6	-3.874	-3.933	0.059
50	7	-3.760	-3.838	0.078
50	8	-3.874	-3.762	-0.112
50	9	-3.798	-3.762	-0.036
50	10	-3.817	-3.838	0.021
100	B011	-3.836	-3.837	0.001
100	B012	-3.874	-3.875	0.001
100	B013	-3.779	-3.818	0.039
100	B014	-3.817	-3.856	0.039
100	B015	-3.874	-3.913	0.039
	Max	-3.760	-3.730	0.078
	Average	-3.827	-3.822	-0.005
	Min	-3.874	-3.933	-0.144
	Std Dev	0.044	0.060	0.065

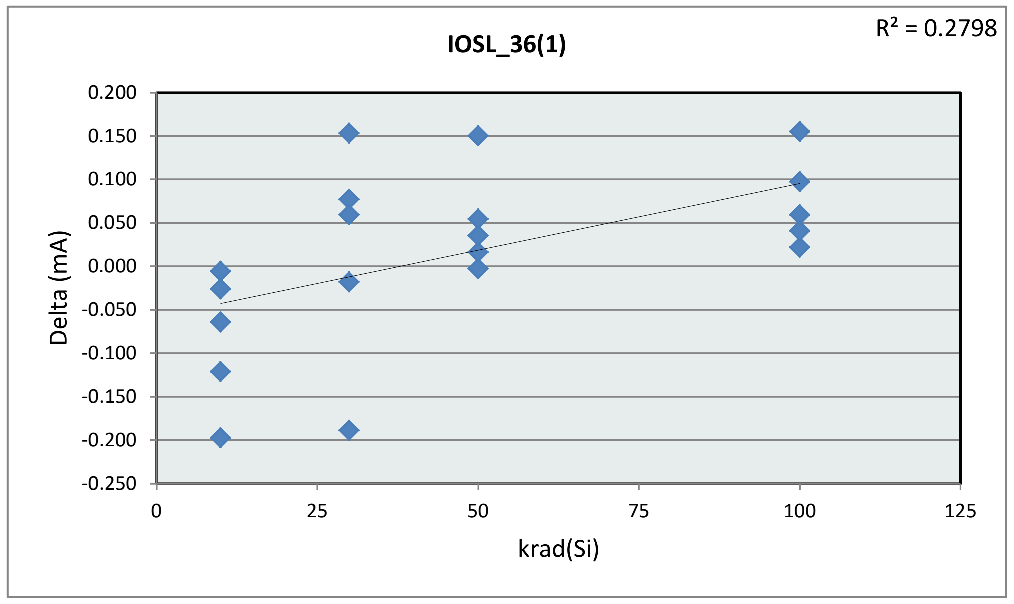


	IOSB_36(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-3.881	-3.908	-3.933	-3.913
Average	-3.798	-3.805	-3.827	-3.860
Max	-3.730	-3.737	-3.762	-3.818
UL	8.000	8.000	8.000	8.000

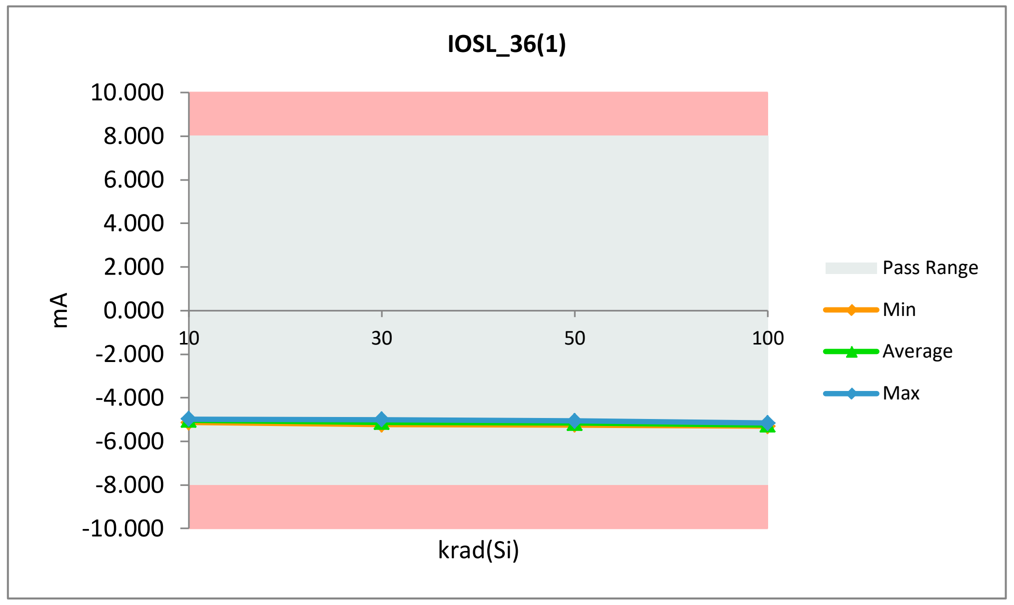


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-5.254	-5.133	-0.121
10	7	-5.083	-5.019	-0.064
10	8	-5.197	-5.000	-0.197
10	9	-4.987	-4.981	-0.006
10	10	-5.026	-5.000	-0.026
30	6	-5.254	-5.236	-0.018
30	7	-5.083	-5.160	0.077
30	8	-5.197	-5.008	-0.189
30	9	-4.987	-5.046	0.059
30	10	-5.026	-5.179	0.153
50	6	-5.254	-5.251	-0.003
50	7	-5.083	-5.137	0.054
50	8	-5.197	-5.213	0.016
50	9	-4.987	-5.137	0.150
50	10	-5.026	-5.061	0.035
100	B011	-5.064	-5.161	0.097
100	B012	-5.121	-5.276	0.155
100	B013	-5.121	-5.180	0.059
100	B014	-5.292	-5.314	0.022
100	B015	-5.254	-5.295	0.041
	Max	-4.987	-4.981	0.155
	Average	-5.125	-5.139	0.015
	Min	-5.292	-5.314	-0.197
	Std Dev	0.104	0.107	0.100

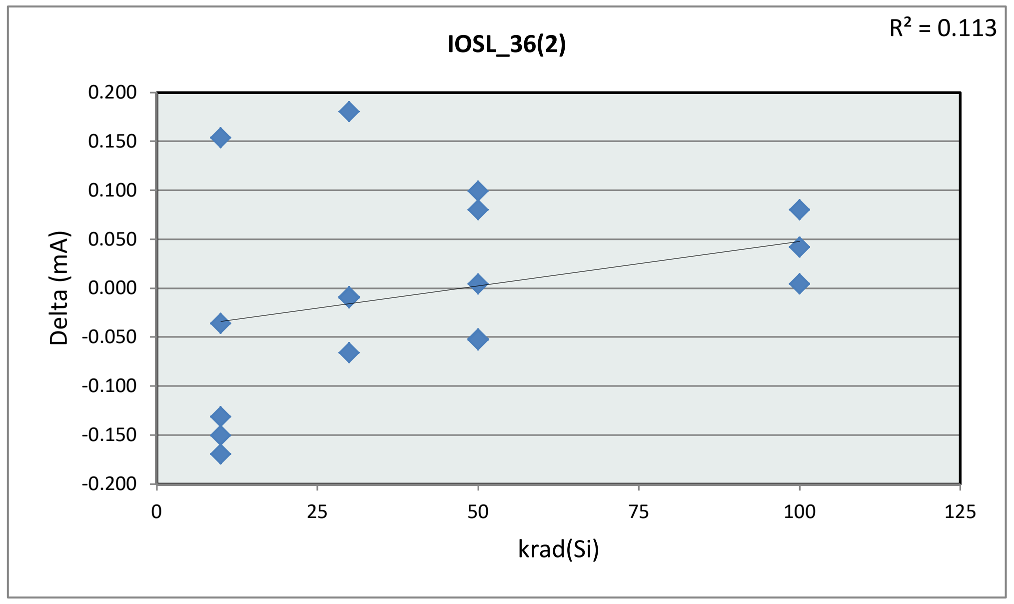


	IOSL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.133	-5.236	-5.251	-5.314
Average	-5.026	-5.126	-5.160	-5.245
Max	-4.981	-5.008	-5.061	-5.161
UL	8.000	8.000	8.000	8.000

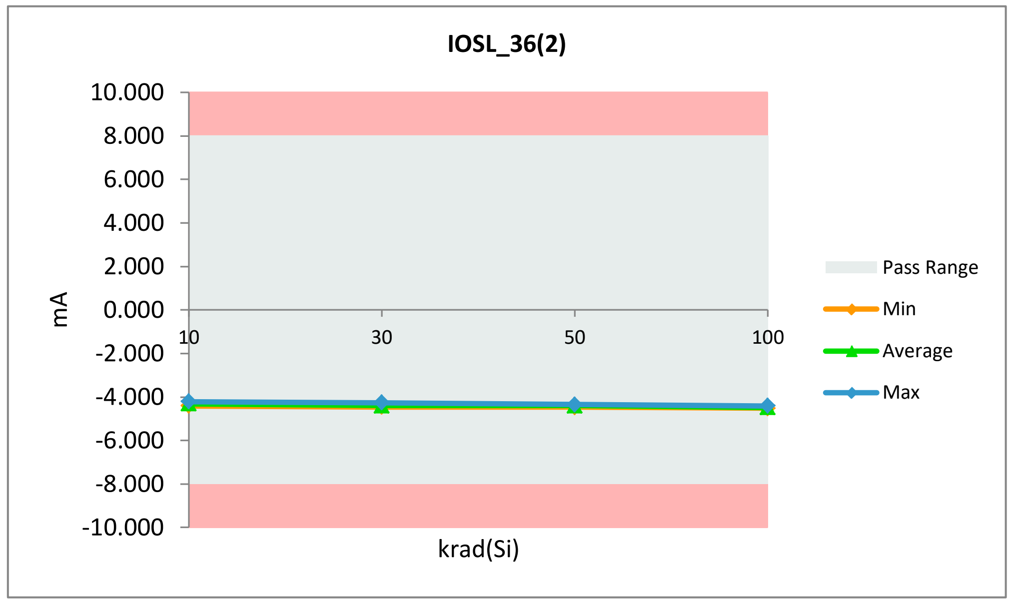


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-4.520	-4.351	-0.169
10	7	-4.368	-4.218	-0.150
10	8	-4.463	-4.332	-0.131
10	9	-4.273	-4.237	-0.036
10	10	-4.254	-4.408	0.154
30	6	-4.520	-4.454	-0.066
30	7	-4.368	-4.358	-0.010
30	8	-4.463	-4.454	-0.009
30	9	-4.273	-4.263	-0.010
30	10	-4.254	-4.434	0.180
50	6	-4.520	-4.468	-0.052
50	7	-4.368	-4.372	0.004
50	8	-4.463	-4.410	-0.053
50	9	-4.273	-4.353	0.080
50	10	-4.254	-4.353	0.099
100	B011	-4.368	-4.410	0.042
100	B012	-4.444	-4.524	0.080
100	B013	-4.406	-4.448	0.042
100	B014	-4.520	-4.524	0.004
100	B015	-4.520	-4.524	0.004
	Max	-4.254	-4.218	0.180
	Average	-4.395	-4.395	0.000
	Min	-4.520	-4.524	-0.169
	Std Dev	0.103	0.090	0.092

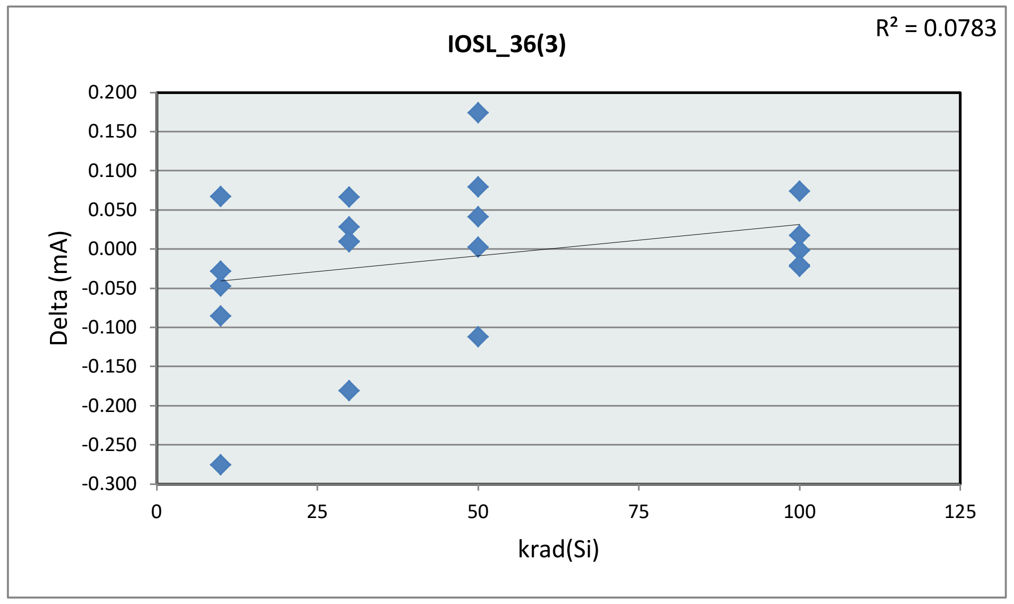


	IOSL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.408	-4.454	-4.468	-4.524
Average	-4.309	-4.393	-4.391	-4.486
Max	-4.218	-4.263	-4.353	-4.410
UL	8.000	8.000	8.000	8.000

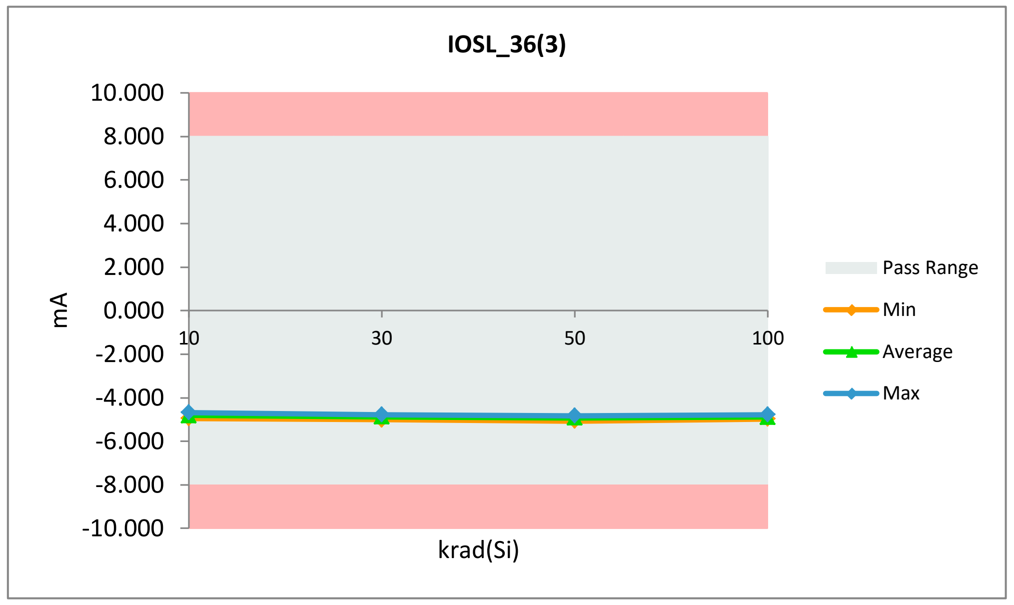


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOSL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	-8	-8	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-4.994	-4.947	-0.047
10	7	-4.823	-4.794	-0.029
10	8	-4.956	-4.680	-0.276
10	9	-4.823	-4.737	-0.086
10	10	-4.842	-4.909	0.067
30	6	-4.994	-5.004	0.010
30	7	-4.823	-4.851	0.028
30	8	-4.956	-4.775	-0.181
30	9	-4.823	-4.832	0.009
30	10	-4.842	-4.908	0.066
50	6	-4.994	-5.073	0.079
50	7	-4.823	-4.864	0.041
50	8	-4.956	-4.844	-0.112
50	9	-4.823	-4.825	0.002
50	10	-4.842	-5.016	0.174
100	B011	-4.899	-4.897	-0.002
100	B012	-4.861	-4.935	0.074
100	B013	-4.804	-4.782	-0.022
100	B014	-4.861	-4.878	0.017
100	B015	-4.994	-4.973	-0.021
	Max	-4.804	-4.680	0.174
	Average	-4.887	-4.876	-0.010
	Min	-4.994	-5.073	-0.276
	Std Dev	0.072	0.099	0.098



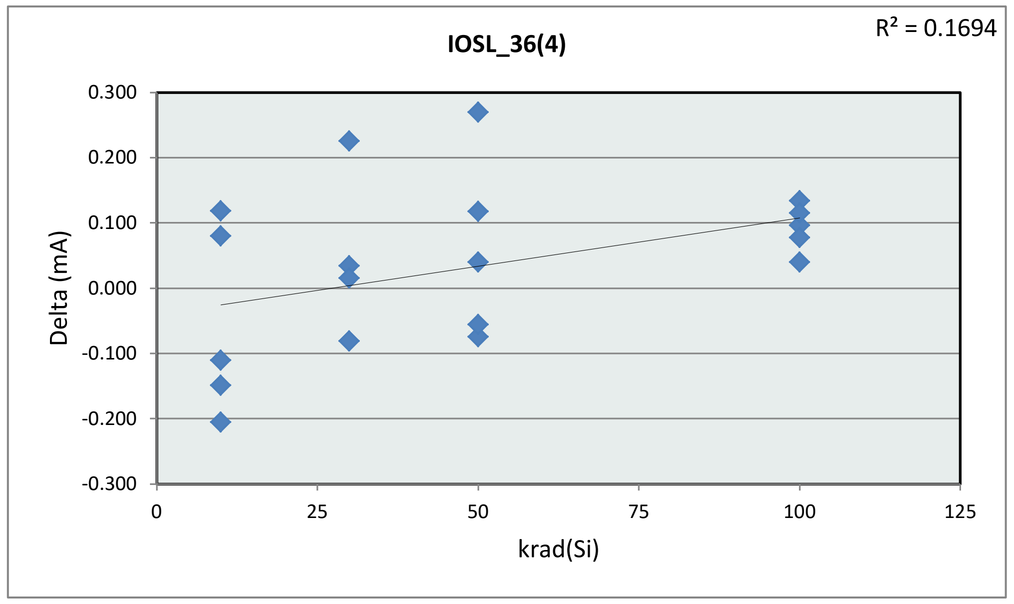
	IOSL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	8	mA		
Min Limit	-8	mA		
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-4.947	-5.004	-5.073	-4.973
Average	-4.813	-4.874	-4.924	-4.893
Max	-4.680	-4.775	-4.825	-4.782
UL	8.000	8.000	8.000	8.000



LDR UnBiased TID Report
SN55LVCP22A-SP

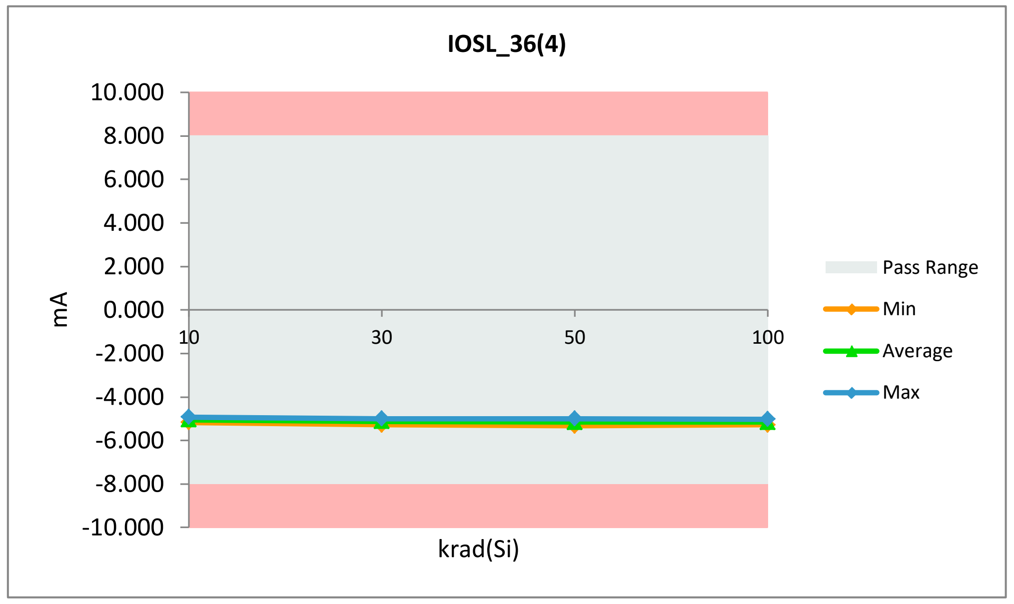
	IOSL_36(4)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mA	mA
Max Limit	8	8
Min Limit	-8	-8

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	-5.054	-5.172	0.118
10	7	-5.054	-5.134	0.080
10	8	-5.074	-4.925	-0.149
10	9	-5.150	-4.944	-0.206
10	10	-5.150	-5.039	-0.111
30	6	-5.054	-5.279	0.225
30	7	-5.054	-5.088	0.034
30	8	-5.074	-4.993	-0.081
30	9	-5.150	-5.069	-0.081
30	10	-5.150	-5.165	0.015
50	6	-5.054	-5.323	0.269
50	7	-5.054	-5.171	0.117
50	8	-5.074	-4.999	-0.075
50	9	-5.150	-5.094	-0.056
50	10	-5.150	-5.190	0.040
100	B011	-5.112	-5.208	0.096
100	B012	-5.150	-5.284	0.134
100	B013	-4.902	-5.017	0.115
100	B014	-5.112	-5.189	0.077
100	B015	-5.054	-5.094	0.040
	Max	-4.902	-4.925	0.269
	Average	-5.089	-5.119	0.030
	Min	-5.150	-5.323	-0.206
	Std Dev	0.061	0.112	0.123



	IOSL_36(4)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	8	mA
Min Limit	-8	mA

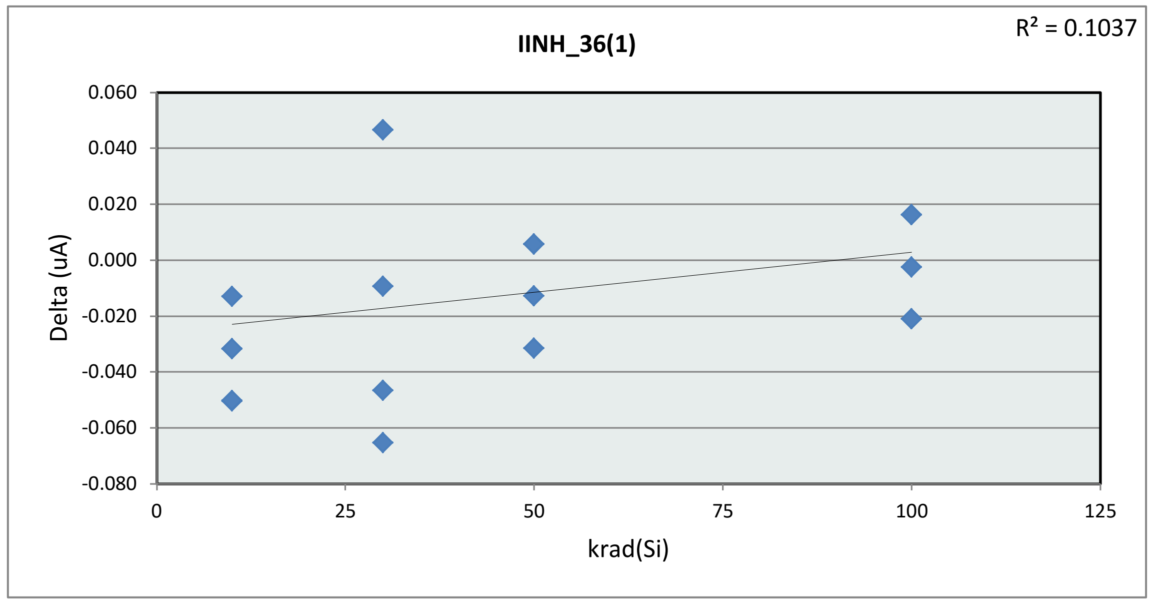
krad(Si)	10	30	50	100
LL	-8.000	-8.000	-8.000	-8.000
Min	-5.172	-5.279	-5.323	-5.284
Average	-5.043	-5.119	-5.155	-5.158
Max	-4.925	-4.993	-4.999	-5.017
UL	8.000	8.000	8.000	8.000



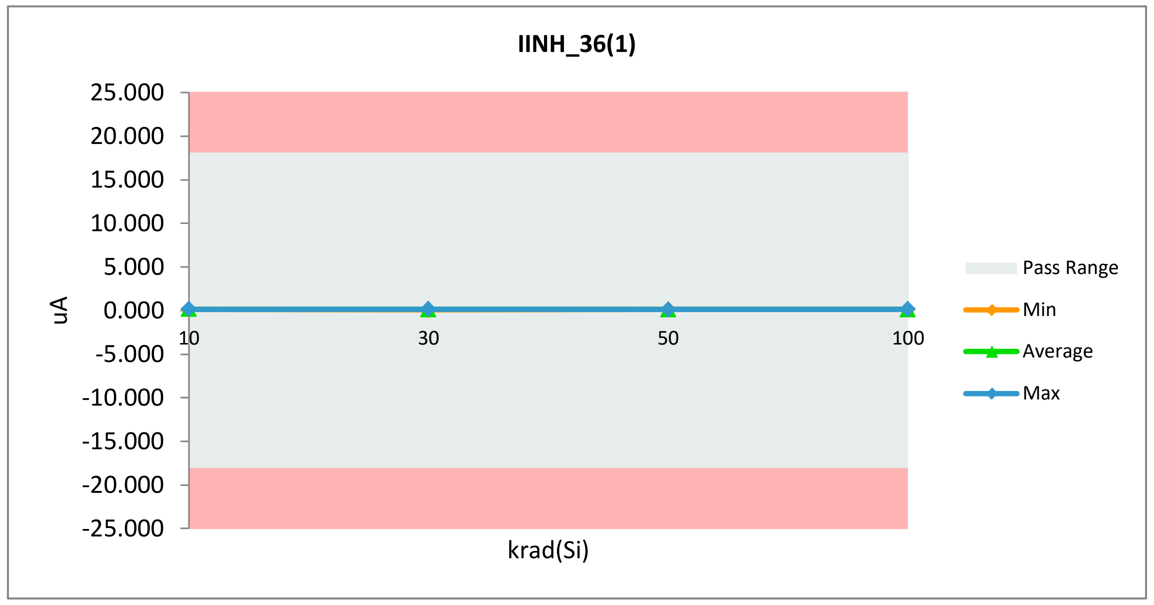
LDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_36(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.120	0.152	-0.032
10	7	0.120	0.133	-0.013
10	8	0.120	0.152	-0.032
10	9	0.083	0.133	-0.050
10	10	0.101	0.152	-0.050
30	6	0.120	0.073	0.047
30	7	0.120	0.167	-0.047
30	8	0.120	0.073	0.047
30	9	0.083	0.092	-0.009
30	10	0.101	0.167	-0.065
50	6	0.120	0.114	0.006
50	7	0.120	0.114	0.006
50	8	0.120	0.114	0.006
50	9	0.083	0.114	-0.032
50	10	0.101	0.114	-0.013
100	B011	0.101	0.122	-0.021
100	B012	0.139	0.122	0.016
100	B013	0.157	0.141	0.016
100	B014	0.120	0.122	-0.002
100	B015	0.120	0.141	-0.021
	Max	0.157	0.167	0.047
	Average	0.113	0.126	-0.012
	Min	0.083	0.073	-0.065
	Std Dev	0.018	0.026	0.031



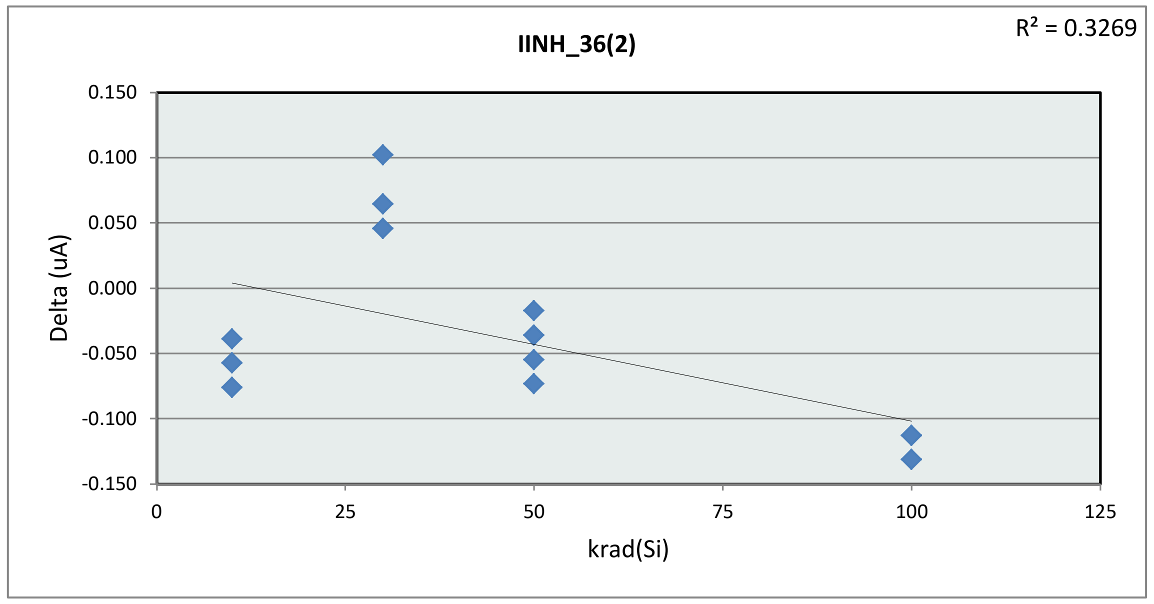
	IINH_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.133	0.073	0.114	0.122
Average	0.144	0.114	0.114	0.130
Max	0.152	0.167	0.114	0.141
UL	18.000	18.000	18.000	18.000



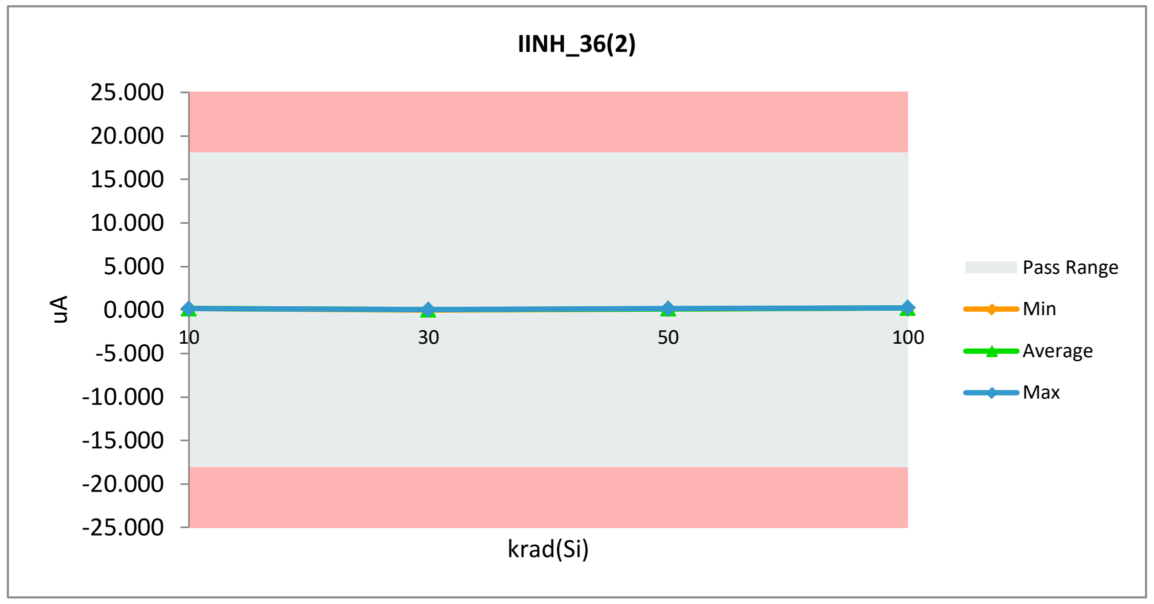
LDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_36(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.084	0.160	-0.076
10	7	0.103	0.141	-0.039
10	8	0.103	0.160	-0.057
10	9	0.084	0.141	-0.057
10	10	0.084	0.160	-0.076
30	6	0.084	0.038	0.046
30	7	0.103	0.001	0.102
30	8	0.103	0.038	0.064
30	9	0.084	0.019	0.064
30	10	0.084	0.038	0.046
50	6	0.084	0.157	-0.073
50	7	0.103	0.120	-0.017
50	8	0.103	0.139	-0.036
50	9	0.084	0.120	-0.036
50	10	0.084	0.139	-0.055
100	B011	0.103	0.215	-0.113
100	B012	0.103	0.215	-0.113
100	B013	0.103	0.234	-0.131
100	B014	0.103	0.215	-0.113
100	B015	0.084	0.215	-0.131
	Max	0.103	0.234	0.102
	Average	0.093	0.133	-0.040
	Min	0.084	0.001	-0.131
	Std Dev	0.010	0.072	0.070

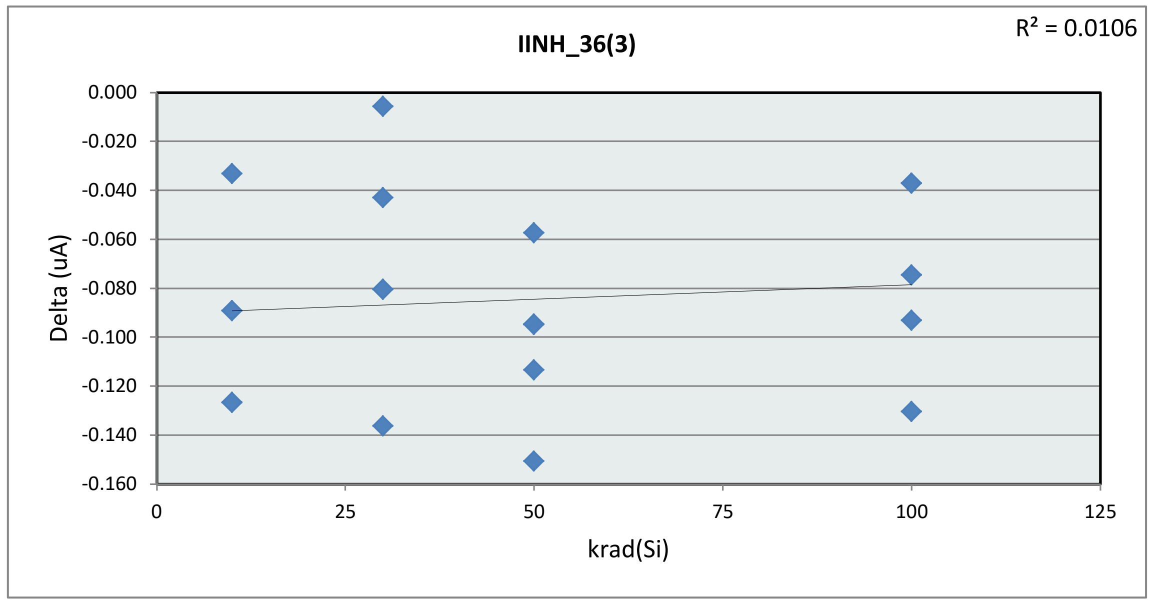


	IINH_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.141	0.001	0.120	0.215
Average	0.153	0.027	0.135	0.219
Max	0.160	0.038	0.157	0.234
UL	18.000	18.000	18.000	18.000

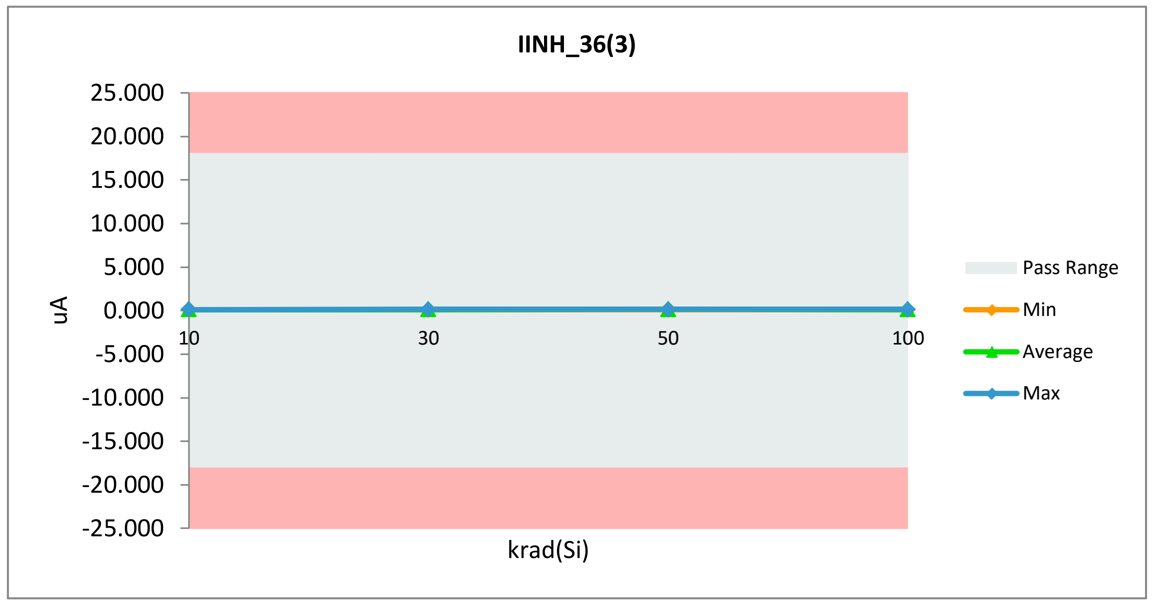


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	0.011	0.138	-0.127
10	7	0.030	0.119	-0.089
10	8	0.049	0.138	-0.089
10	9	0.011	0.138	-0.127
10	10	0.105	0.138	-0.033
30	6	0.011	0.148	-0.136
30	7	0.030	0.110	-0.080
30	8	0.049	0.092	-0.043
30	9	0.011	0.092	-0.080
30	10	0.105	0.110	-0.006
50	6	0.011	0.162	-0.151
50	7	0.030	0.125	-0.095
50	8	0.049	0.143	-0.095
50	9	0.011	0.125	-0.113
50	10	0.105	0.162	-0.057
100	B011	0.067	0.105	-0.037
100	B012	0.011	0.142	-0.131
100	B013	0.086	0.123	-0.037
100	B014	0.030	0.105	-0.075
100	B015	0.011	0.105	-0.093
	Max	0.105	0.162	-0.006
	Average	0.041	0.126	-0.085
	Min	0.011	0.092	-0.151
	Std Dev	0.034	0.021	0.040

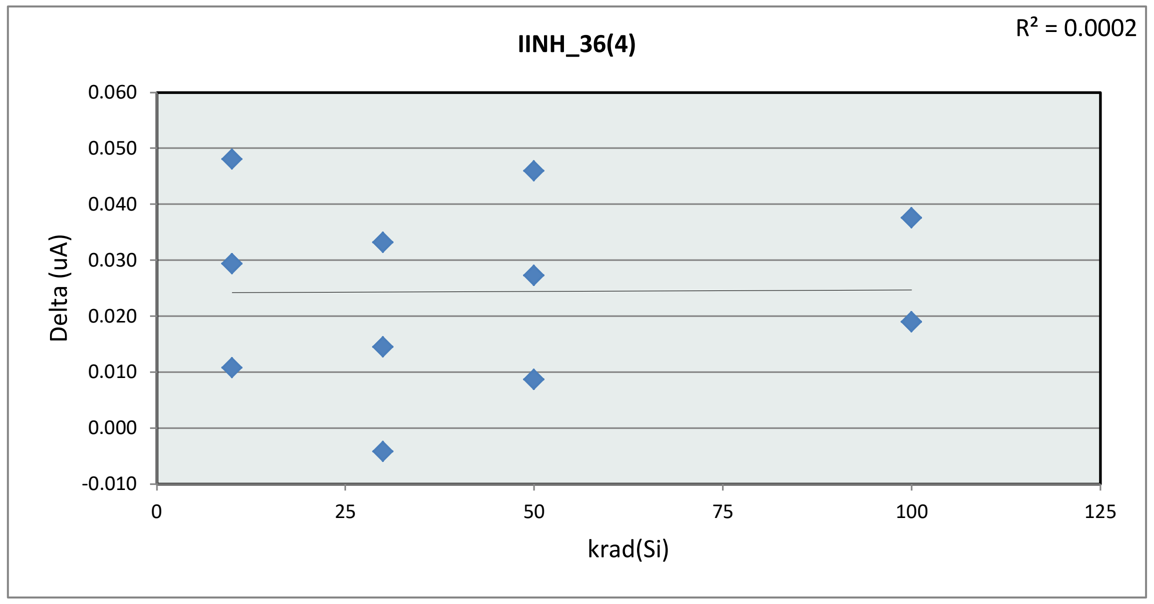


	IINH_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.119	0.092	0.125	0.105
Average	0.134	0.110	0.143	0.116
Max	0.138	0.148	0.162	0.142
UL	18.000	18.000	18.000	18.000

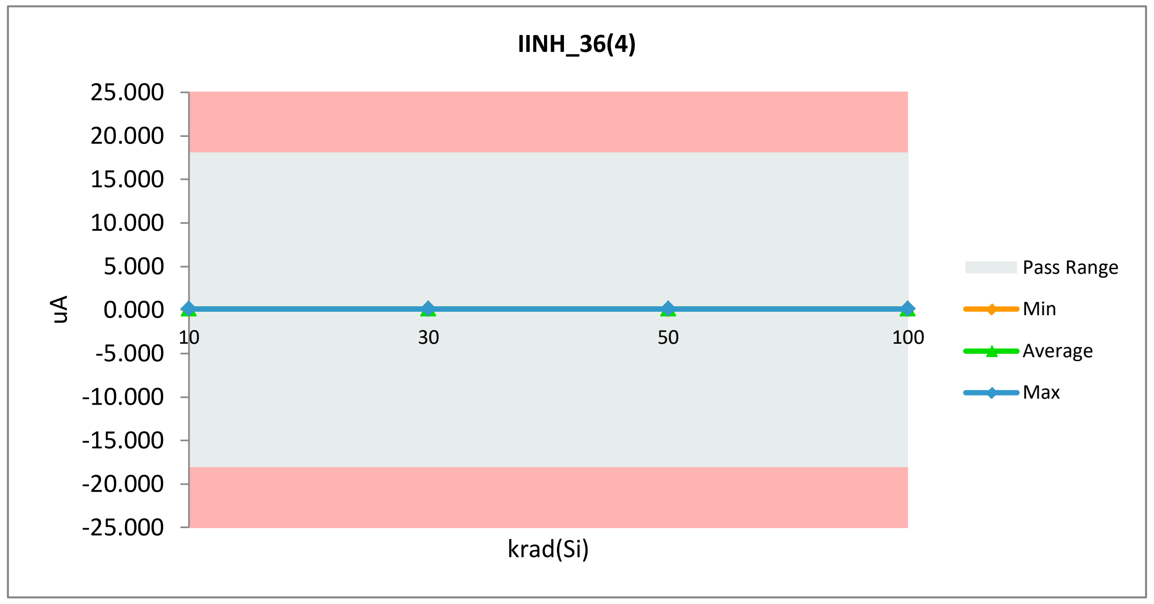


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	0.145	0.116	0.029
10	7	0.145	0.097	0.048
10	8	0.145	0.116	0.029
10	9	0.127	0.097	0.029
10	10	0.127	0.116	0.011
30	6	0.145	0.112	0.033
30	7	0.145	0.112	0.033
30	8	0.145	0.131	0.014
30	9	0.127	0.112	0.014
30	10	0.127	0.131	-0.004
50	6	0.145	0.118	0.027
50	7	0.145	0.099	0.046
50	8	0.145	0.118	0.027
50	9	0.127	0.118	0.009
50	10	0.127	0.118	0.009
100	B011	0.145	0.126	0.019
100	B012	0.145	0.108	0.038
100	B013	0.164	0.126	0.038
100	B014	0.145	0.126	0.019
100	B015	0.145	0.126	0.019
	Max	0.164	0.131	0.048
	Average	0.141	0.116	0.024
	Min	0.127	0.097	-0.004
	Std Dev	0.010	0.010	0.013

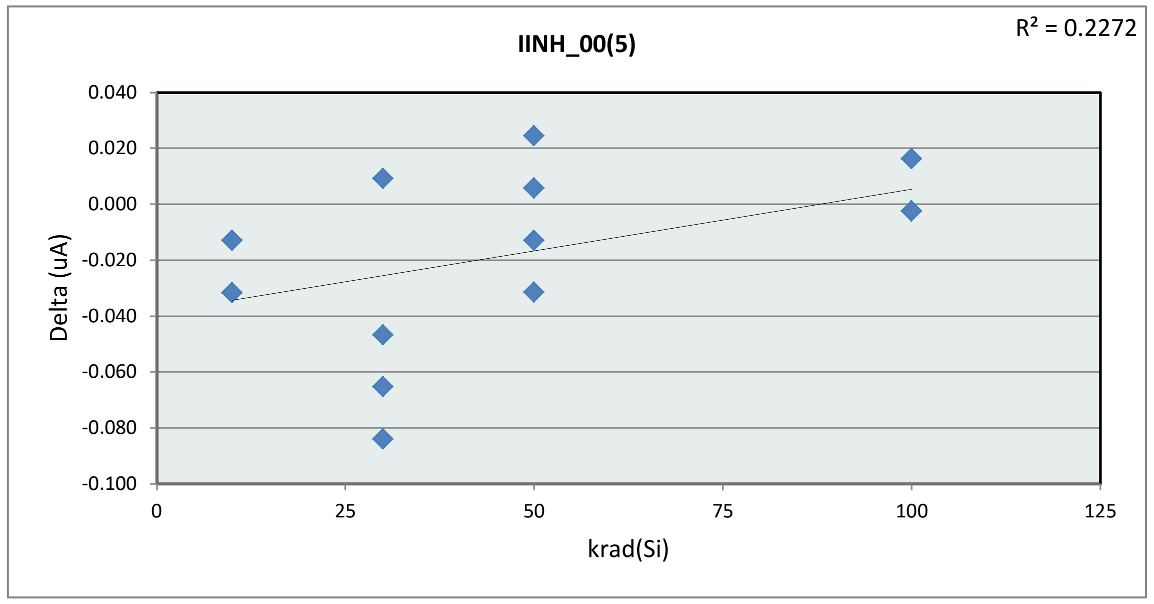


	IINH_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.097	0.112	0.099	0.108
Average	0.109	0.120	0.114	0.123
Max	0.116	0.131	0.118	0.126
UL	18.000	18.000	18.000	18.000

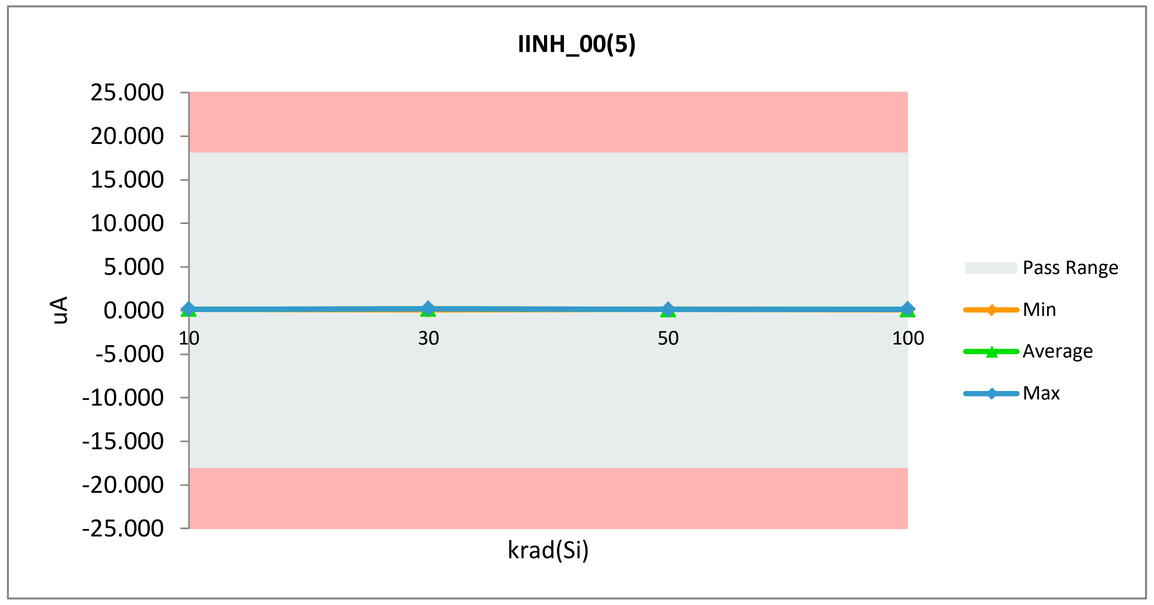


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINH_00(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.120	0.133	-0.013
10	7	0.120	0.133	-0.013
10	8	0.139	0.152	-0.013
10	9	0.101	0.133	-0.032
10	10	0.120	0.152	-0.032
30	6	0.120	0.204	-0.084
30	7	0.120	0.204	-0.084
30	8	0.139	0.204	-0.065
30	9	0.101	0.092	0.009
30	10	0.120	0.167	-0.047
50	6	0.120	0.114	0.006
50	7	0.120	0.114	0.006
50	8	0.139	0.114	0.024
50	9	0.101	0.133	-0.032
50	10	0.120	0.133	-0.013
100	B011	0.101	0.104	-0.003
100	B012	0.120	0.104	0.016
100	B013	0.157	0.141	0.016
100	B014	0.101	0.104	-0.003
100	B015	0.120	0.122	-0.002
	Max	0.157	0.204	0.024
	Average	0.120	0.138	-0.018
	Min	0.101	0.092	-0.084
	Std Dev	0.015	0.034	0.032



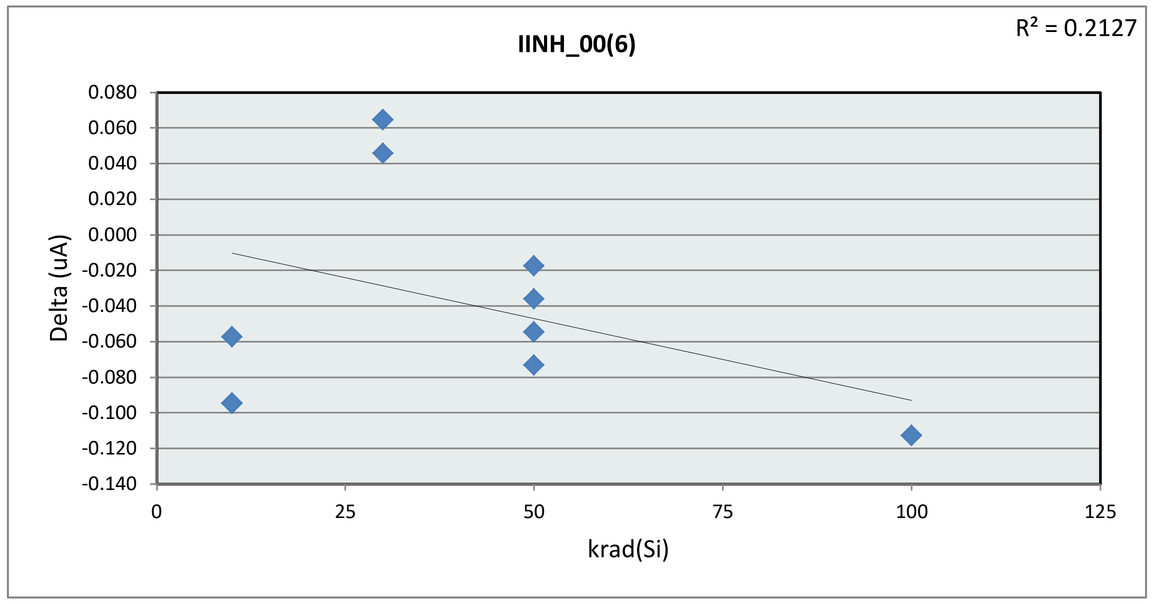
	IINH_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.133	0.092	0.114	0.104
Average	0.140	0.174	0.122	0.115
Max	0.152	0.204	0.133	0.141
UL	18.000	18.000	18.000	18.000



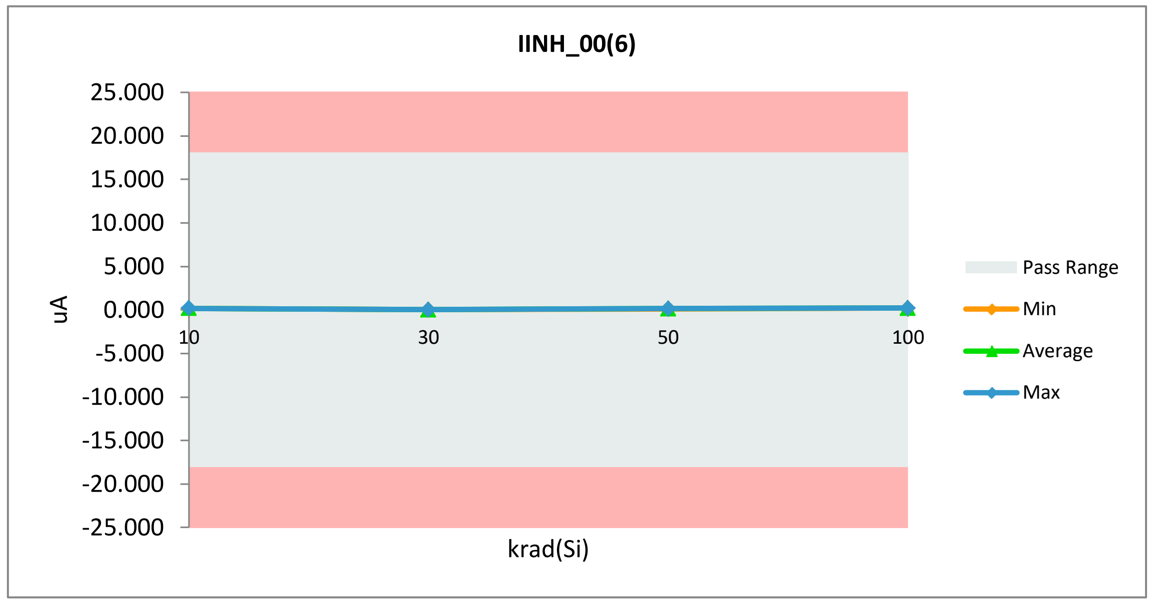
LDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_00(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	0.103	0.197	-0.095
10	7	0.103	0.160	-0.057
10	8	0.103	0.160	-0.057
10	9	0.084	0.179	-0.095
10	10	0.084	0.179	-0.095
30	6	0.103	0.038	0.064
30	7	0.103	0.038	0.064
30	8	0.103	0.038	0.064
30	9	0.084	0.019	0.064
30	10	0.084	0.038	0.046
50	6	0.103	0.157	-0.055
50	7	0.103	0.120	-0.017
50	8	0.103	0.157	-0.055
50	9	0.084	0.120	-0.036
50	10	0.084	0.157	-0.073
100	B011	0.103	0.215	-0.113
100	B012	0.103	0.215	-0.113
100	B013	0.103	0.215	-0.113
100	B014	0.103	0.215	-0.113
100	B015	0.103	0.215	-0.113
	Max	0.103	0.215	0.064
	Average	0.097	0.142	-0.045
	Min	0.084	0.019	-0.113
	Std Dev	0.009	0.070	0.068



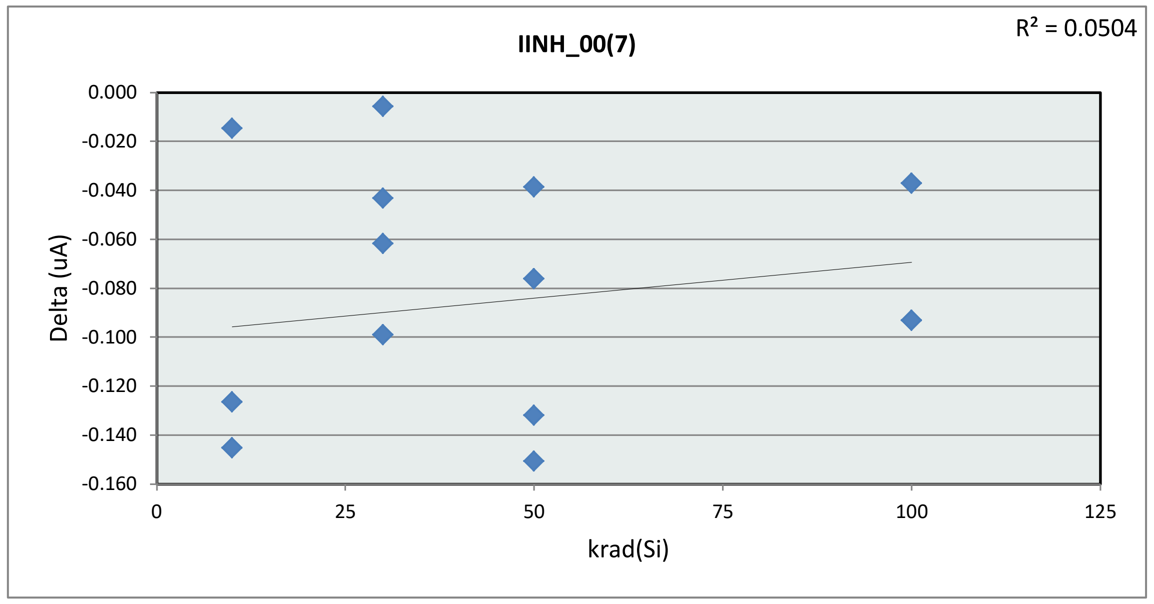
	IINH_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.160	0.019	0.120	0.215
Average	0.175	0.034	0.142	0.215
Max	0.197	0.038	0.157	0.215
UL	18.000	18.000	18.000	18.000



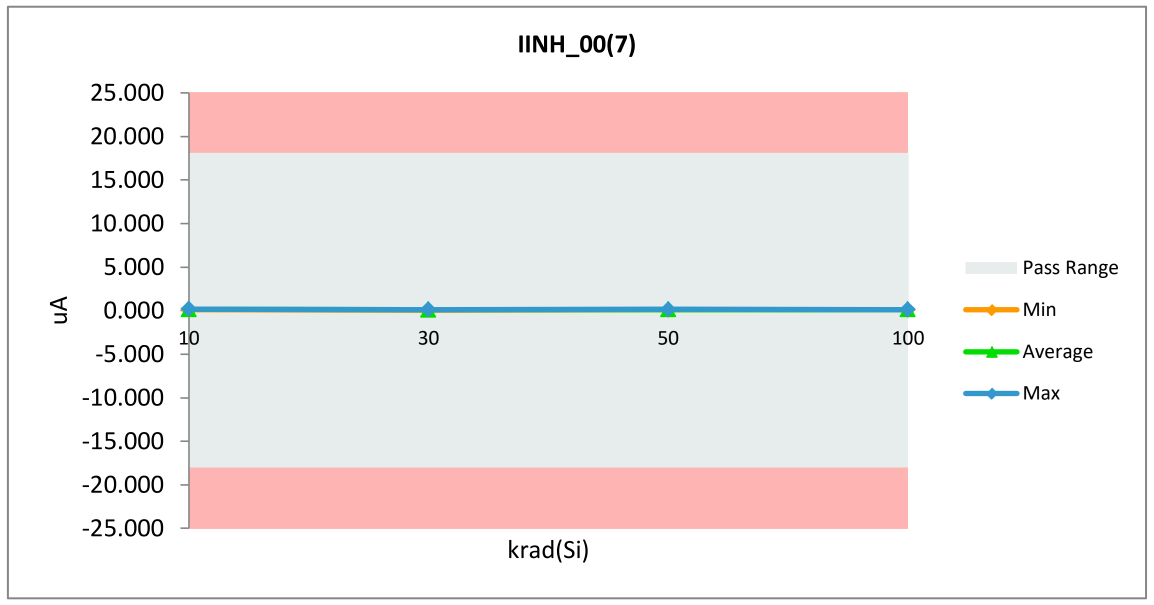
LDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_00(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.011	0.157	-0.145
10	7	0.030	0.157	-0.127
10	8	0.086	0.101	-0.015
10	9	0.030	0.175	-0.145
10	10	0.049	0.175	-0.127
30	6	0.011	0.110	-0.099
30	7	0.030	0.073	-0.043
30	8	0.086	0.092	-0.006
30	9	0.030	0.129	-0.099
30	10	0.049	0.110	-0.062
50	6	0.011	0.162	-0.151
50	7	0.030	0.106	-0.076
50	8	0.086	0.125	-0.039
50	9	0.030	0.162	-0.132
50	10	0.049	0.125	-0.076
100	B011	0.011	0.105	-0.093
100	B012	0.067	0.105	-0.037
100	B013	0.086	0.123	-0.037
100	B014	0.011	0.105	-0.093
100	B015	0.011	0.105	-0.093
	Max	0.086	0.175	-0.006
	Average	0.040	0.125	-0.085
	Min	0.011	0.073	-0.151
	Std Dev	0.028	0.030	0.045



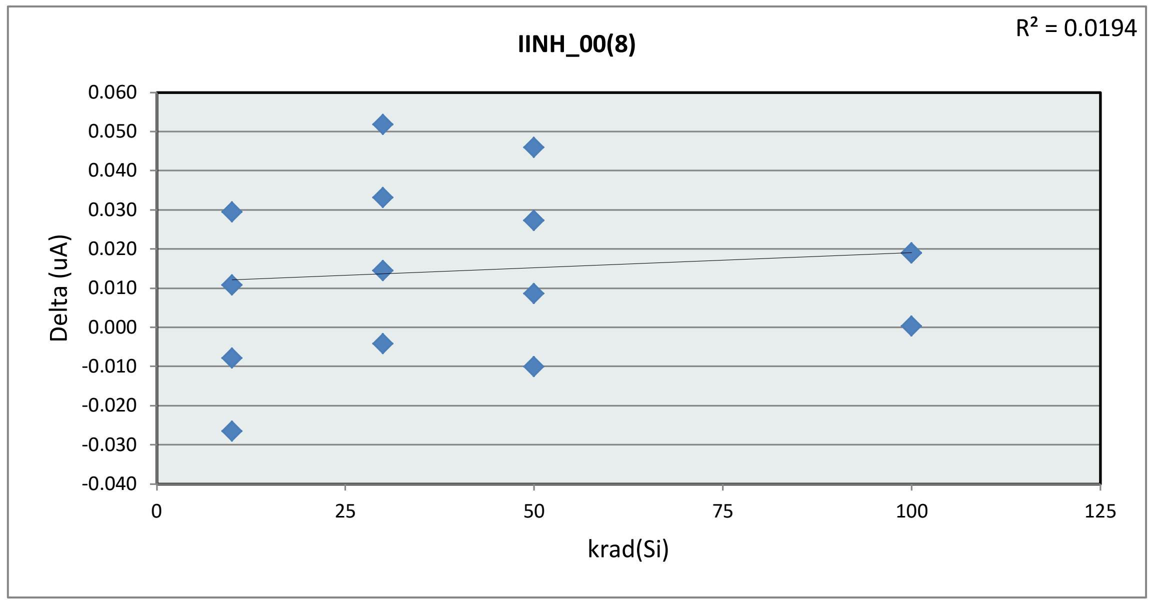
	IINH_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.101	0.073	0.106	0.105
Average	0.153	0.103	0.136	0.108
Max	0.175	0.129	0.162	0.123
UL	18.000	18.000	18.000	18.000



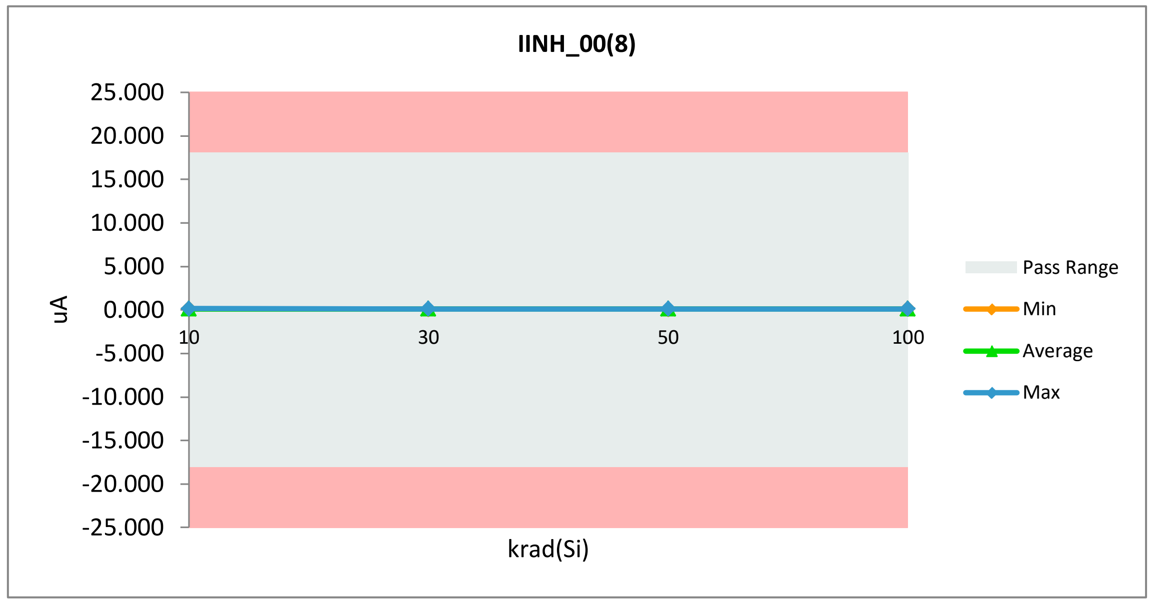
LDR UnBiased TID Report
SN55LVCP22A-SP

	IINH_00(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.145	0.153	-0.008
10	7	0.145	0.135	0.011
10	8	0.145	0.116	0.029
10	9	0.127	0.116	0.011
10	10	0.127	0.153	-0.027
30	6	0.145	0.112	0.033
30	7	0.145	0.094	0.052
30	8	0.145	0.131	0.014
30	9	0.127	0.112	0.014
30	10	0.127	0.131	-0.004
50	6	0.145	0.118	0.027
50	7	0.145	0.099	0.046
50	8	0.145	0.118	0.027
50	9	0.127	0.118	0.009
50	10	0.127	0.137	-0.010
100	B011	0.145	0.126	0.019
100	B012	0.145	0.126	0.019
100	B013	0.145	0.126	0.019
100	B014	0.127	0.126	0.000
100	B015	0.145	0.126	0.019
	Max	0.145	0.153	0.052
	Average	0.139	0.124	0.015
	Min	0.127	0.094	-0.027
	Std Dev	0.009	0.015	0.019

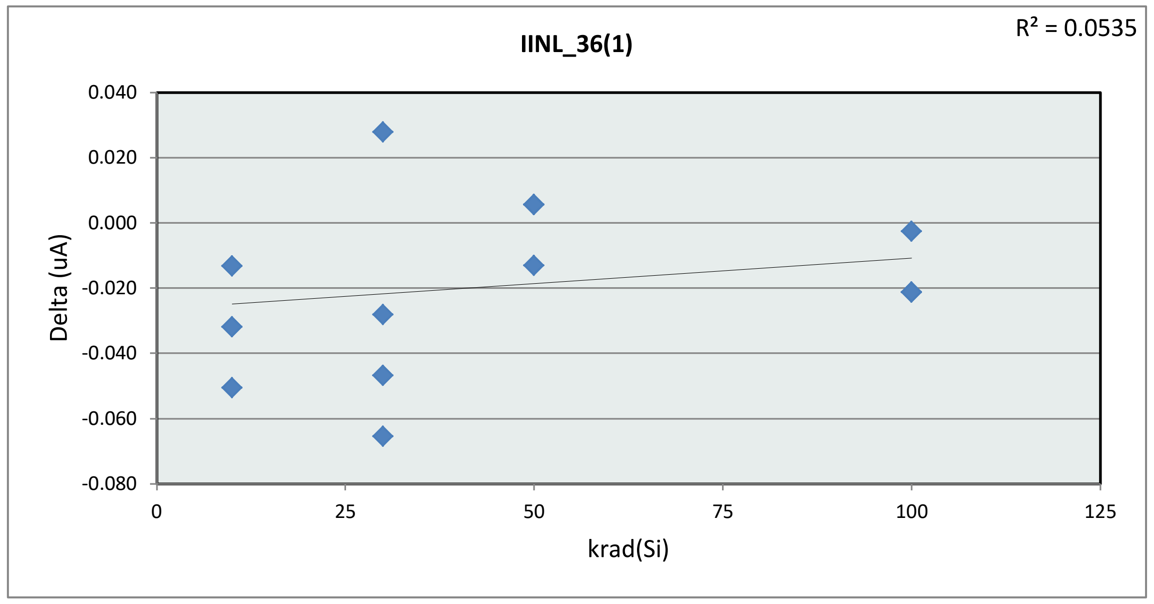


	IINH_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.116	0.094	0.099	0.126
Average	0.135	0.116	0.118	0.126
Max	0.153	0.131	0.137	0.126
UL	18.000	18.000	18.000	18.000

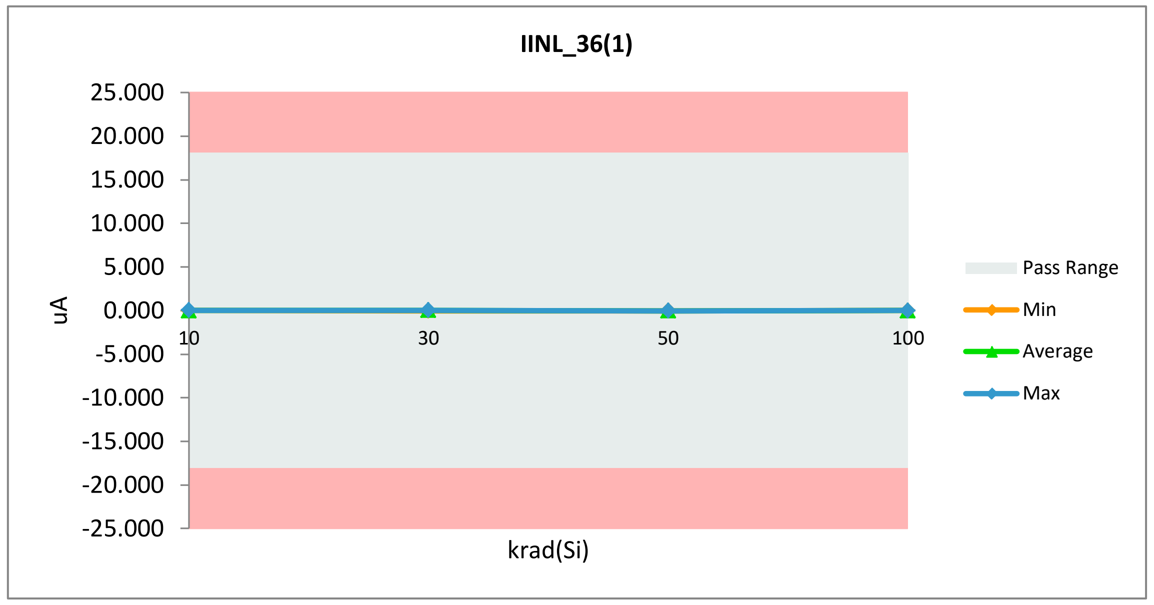


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_36(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.011	0.021	-0.032
10	7	-0.011	0.003	-0.013
10	8	-0.011	0.021	-0.032
10	9	-0.011	0.003	-0.013
10	10	-0.029	0.021	-0.051
30	6	-0.011	-0.038	0.028
30	7	-0.011	0.036	-0.047
30	8	-0.011	0.036	-0.047
30	9	-0.011	0.017	-0.028
30	10	-0.029	0.036	-0.065
50	6	-0.011	-0.016	0.006
50	7	-0.011	-0.016	0.006
50	8	-0.011	-0.016	0.006
50	9	-0.011	-0.016	0.006
50	10	-0.029	-0.016	-0.013
100	B011	-0.029	-0.008	-0.021
100	B012	-0.029	-0.008	-0.021
100	B013	-0.029	-0.008	-0.021
100	B014	-0.029	-0.008	-0.021
100	B015	-0.011	-0.008	-0.003
	Max	-0.011	0.036	0.028
	Average	-0.017	0.002	-0.019
	Min	-0.029	-0.038	-0.065
	Std Dev	0.009	0.021	0.023

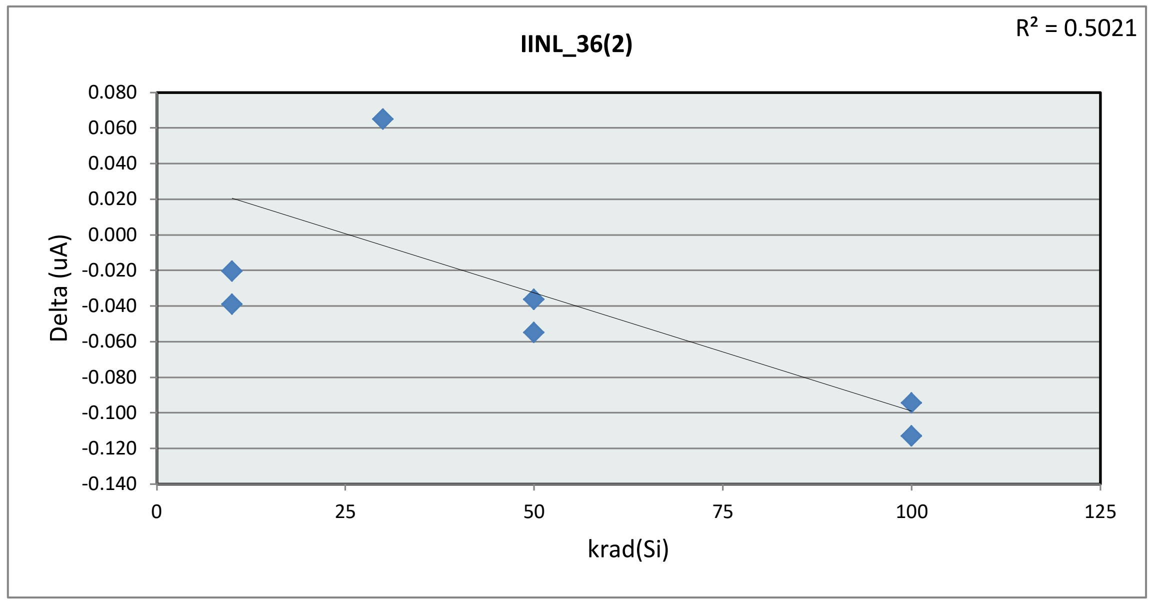


	IINL_36(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.003	-0.038	-0.016	-0.008
Average	0.014	0.017	-0.016	-0.008
Max	0.021	0.036	-0.016	-0.008
UL	18.000	18.000	18.000	18.000

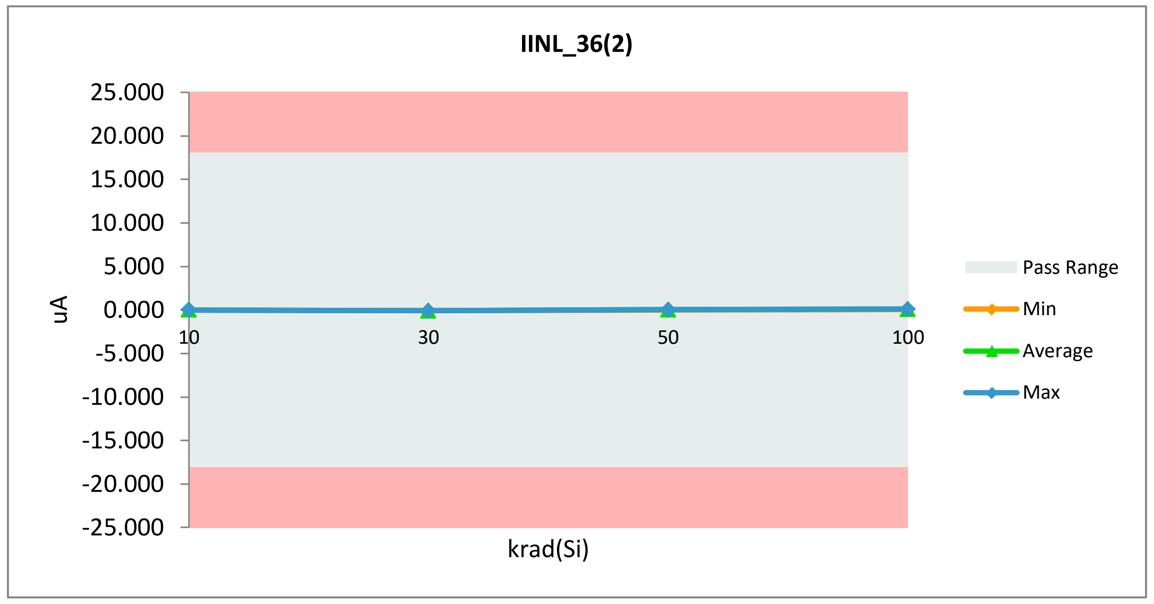


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_36(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.028	-0.008	-0.021
10	7	-0.028	-0.008	-0.021
10	8	-0.028	0.011	-0.039
10	9	-0.028	0.011	-0.039
10	10	-0.028	-0.008	-0.021
30	6	-0.028	-0.093	0.065
30	7	-0.028	-0.093	0.065
30	8	-0.028	-0.093	0.065
30	9	-0.028	-0.093	0.065
30	10	-0.028	-0.093	0.065
50	6	-0.028	0.008	-0.036
50	7	-0.028	0.027	-0.055
50	8	-0.028	0.027	-0.055
50	9	-0.028	0.008	-0.036
50	10	-0.028	0.008	-0.036
100	B011	-0.028	0.085	-0.113
100	B012	-0.028	0.067	-0.095
100	B013	-0.028	0.085	-0.113
100	B014	-0.028	0.085	-0.113
100	B015	-0.028	0.085	-0.113
	Max	-0.028	0.085	0.065
	Average	-0.028	0.001	-0.029
	Min	-0.028	-0.093	-0.113
	Std Dev	0.000	0.064	0.064

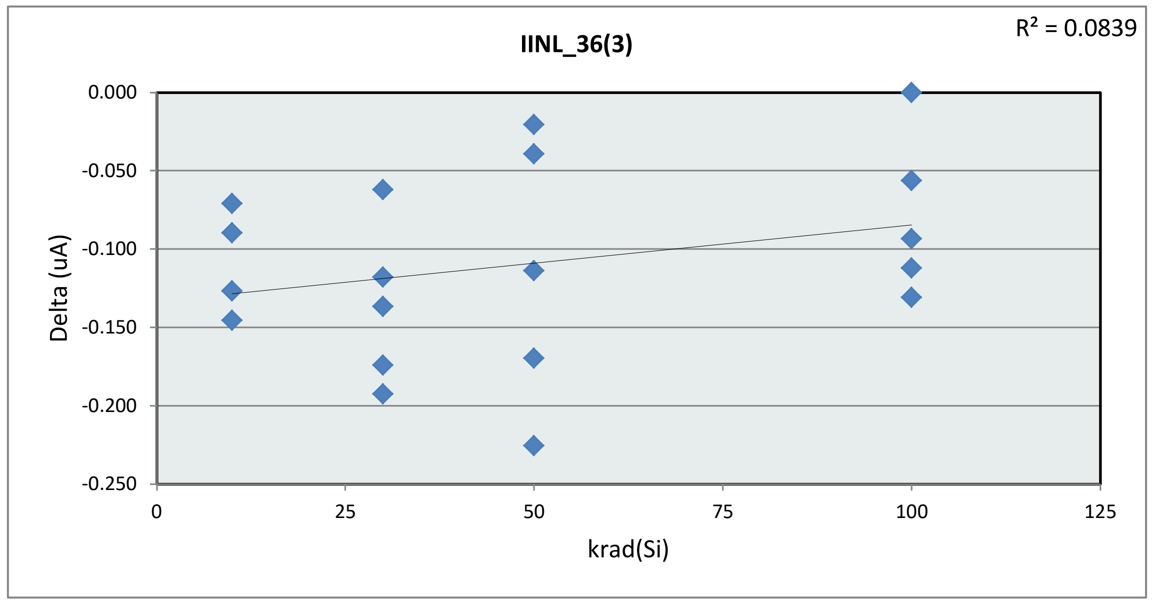


	IINL_36(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.008	-0.093	0.008	0.067
Average	0.000	-0.093	0.016	0.081
Max	0.011	-0.093	0.027	0.085
UL	18.000	18.000	18.000	18.000

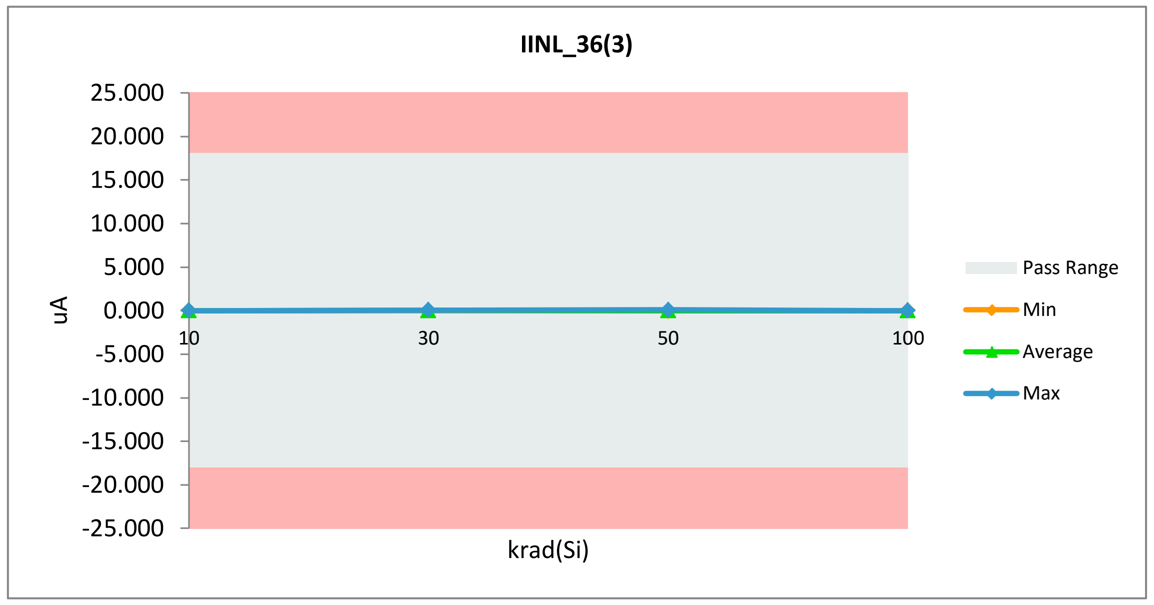


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_36(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-0.138	-0.011	-0.127
10	7	-0.138	0.008	-0.146
10	8	-0.082	0.008	-0.090
10	9	-0.063	0.008	-0.071
10	10	-0.138	-0.011	-0.127
30	6	-0.138	0.055	-0.193
30	7	-0.138	0.036	-0.174
30	8	-0.082	0.036	-0.118
30	9	-0.063	-0.001	-0.062
30	10	-0.138	-0.001	-0.137
50	6	-0.138	0.032	-0.170
50	7	-0.138	-0.024	-0.114
50	8	-0.082	-0.043	-0.039
50	9	-0.063	-0.043	-0.021
50	10	-0.138	0.088	-0.226
100	B011	-0.119	-0.007	-0.112
100	B012	-0.063	-0.007	-0.056
100	B013	-0.101	-0.007	-0.094
100	B014	-0.007	-0.007	0.000
100	B015	-0.138	-0.007	-0.131
	Max	-0.007	0.088	0.000
	Average	-0.105	0.005	-0.110
	Min	-0.138	-0.043	-0.226
	Std Dev	0.039	0.031	0.058

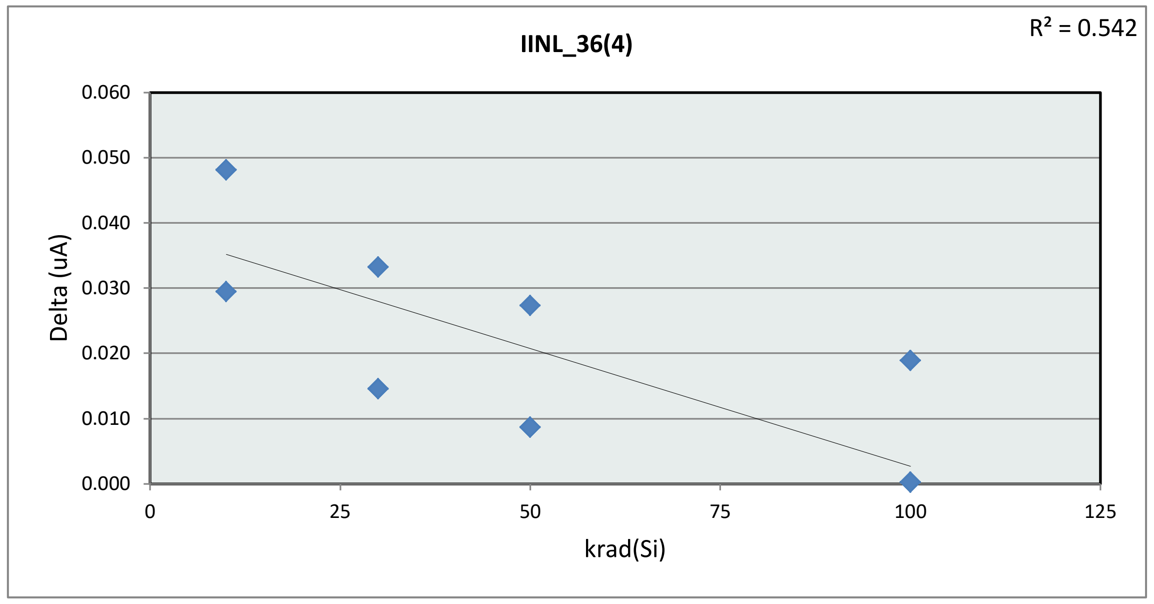


	IINL_36(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.011	-0.001	-0.043	-0.007
Average	0.000	0.025	0.002	-0.007
Max	0.008	0.055	0.088	-0.007
UL	18.000	18.000	18.000	18.000

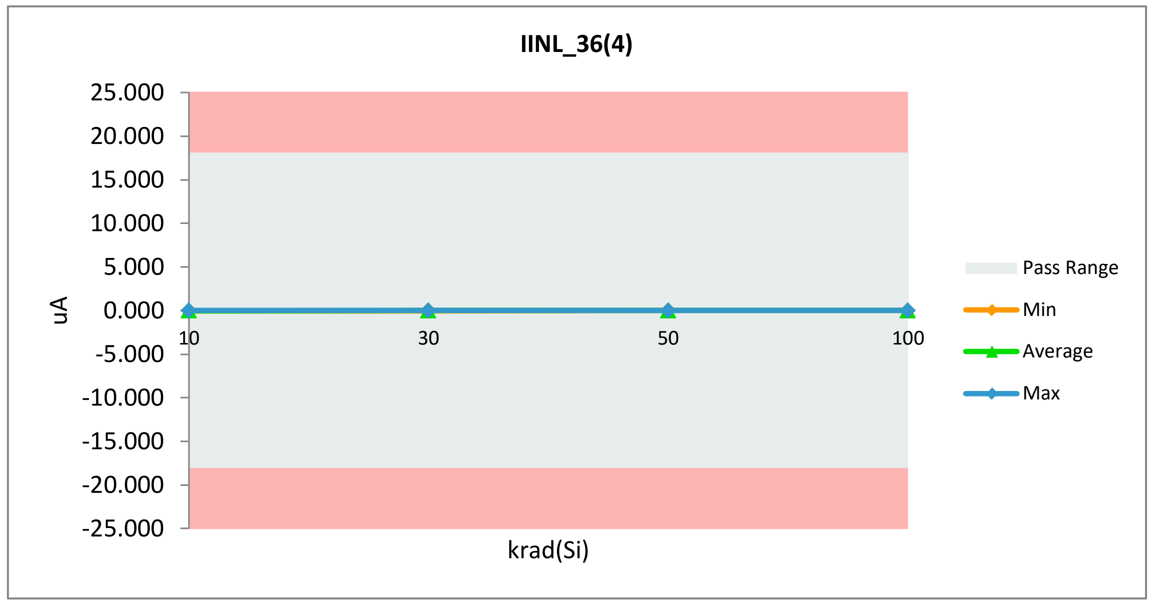


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_36(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbias	Delta
10	6	0.015	-0.033	0.048
10	7	0.015	-0.033	0.048
10	8	0.015	-0.033	0.048
10	9	0.015	-0.033	0.048
10	10	0.015	-0.015	0.029
30	6	0.015	0.000	0.015
30	7	0.015	0.000	0.015
30	8	0.015	-0.018	0.033
30	9	0.015	-0.018	0.033
30	10	0.015	0.000	0.015
50	6	0.015	0.006	0.009
50	7	0.015	-0.012	0.027
50	8	0.015	0.006	0.009
50	9	0.015	0.006	0.009
50	10	0.015	0.006	0.009
100	B011	0.015	-0.004	0.019
100	B012	0.015	0.015	0.000
100	B013	0.015	-0.004	0.019
100	B014	0.015	0.015	0.000
100	B015	0.015	0.015	0.000
	Max	0.015	0.015	0.048
	Average	0.015	-0.007	0.022
	Min	0.015	-0.033	0.000
	Std Dev	0.000	0.017	0.017

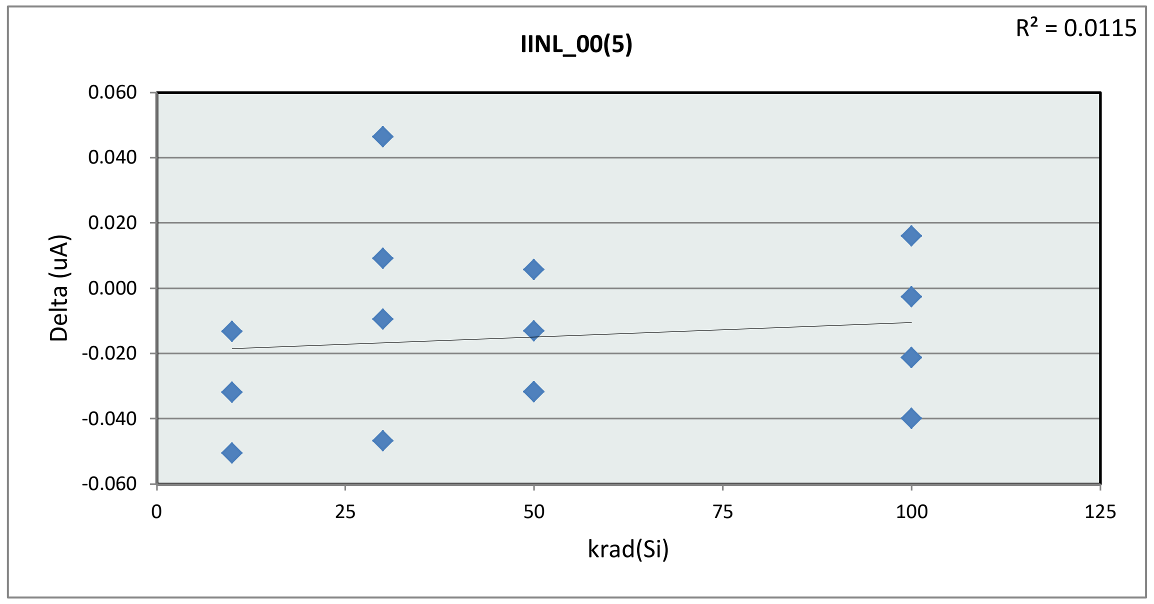


	IINL_36(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.033	-0.018	-0.012	-0.004
Average	-0.029	-0.007	0.002	0.007
Max	-0.015	0.000	0.006	0.015
UL	18.000	18.000	18.000	18.000

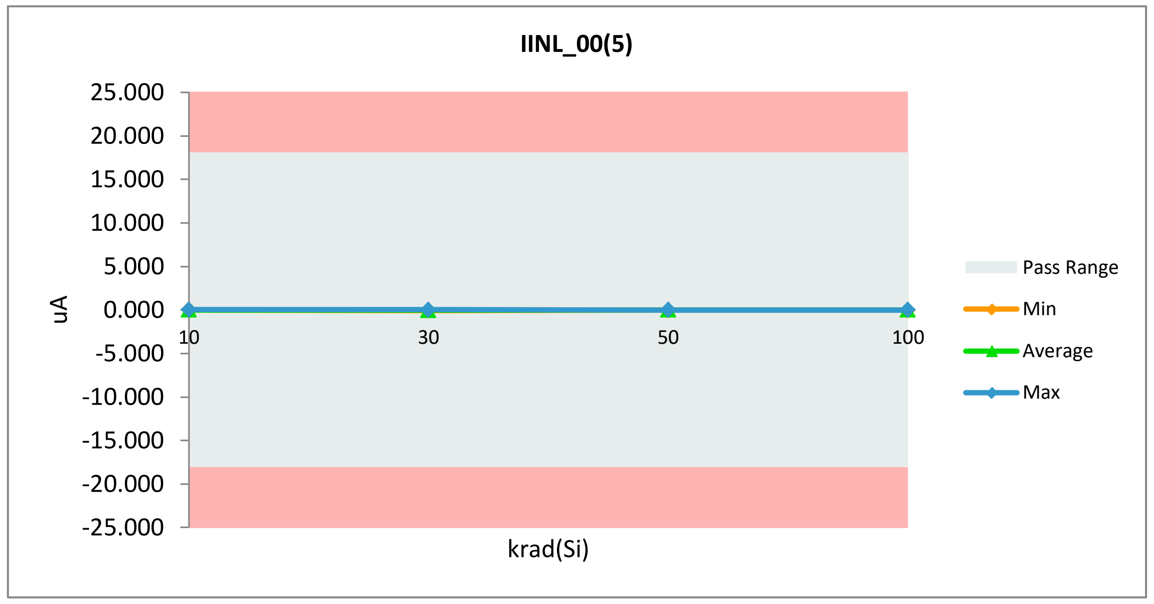


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_00(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.011	0.003	-0.013
10	7	-0.029	0.003	-0.032
10	8	-0.029	0.021	-0.051
10	9	-0.029	0.021	-0.051
10	10	-0.029	0.003	-0.032
30	6	-0.011	-0.001	-0.010
30	7	-0.029	-0.038	0.009
30	8	-0.029	-0.076	0.046
30	9	-0.029	-0.076	0.046
30	10	-0.029	0.017	-0.047
50	6	-0.011	-0.016	0.006
50	7	-0.029	0.002	-0.032
50	8	-0.029	-0.016	-0.013
50	9	-0.029	0.002	-0.032
50	10	-0.029	0.002	-0.032
100	B011	-0.029	-0.008	-0.021
100	B012	-0.029	-0.008	-0.021
100	B013	-0.029	-0.027	-0.003
100	B014	-0.029	0.011	-0.040
100	B015	-0.011	-0.027	0.016
	Max	-0.011	0.021	0.046
	Average	-0.026	-0.010	-0.015
	Min	-0.029	-0.076	-0.051
	Std Dev	0.008	0.027	0.028



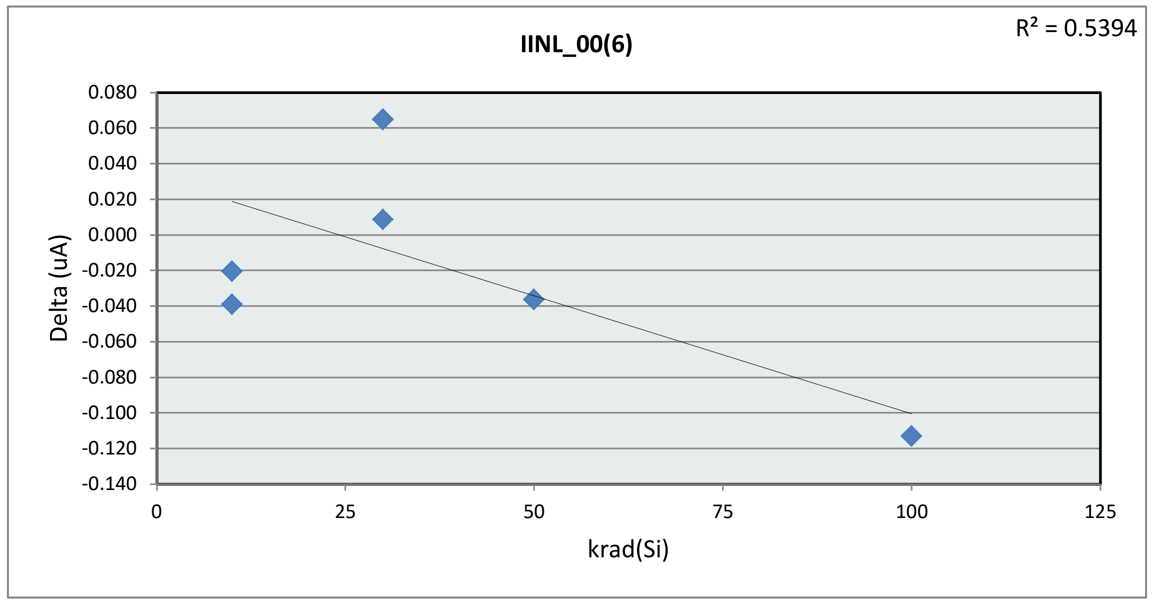
	IINL_00(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	0.003	-0.076	-0.016	-0.027
Average	0.010	-0.035	-0.005	-0.012
Max	0.021	0.017	0.002	0.011
UL	18.000	18.000	18.000	18.000



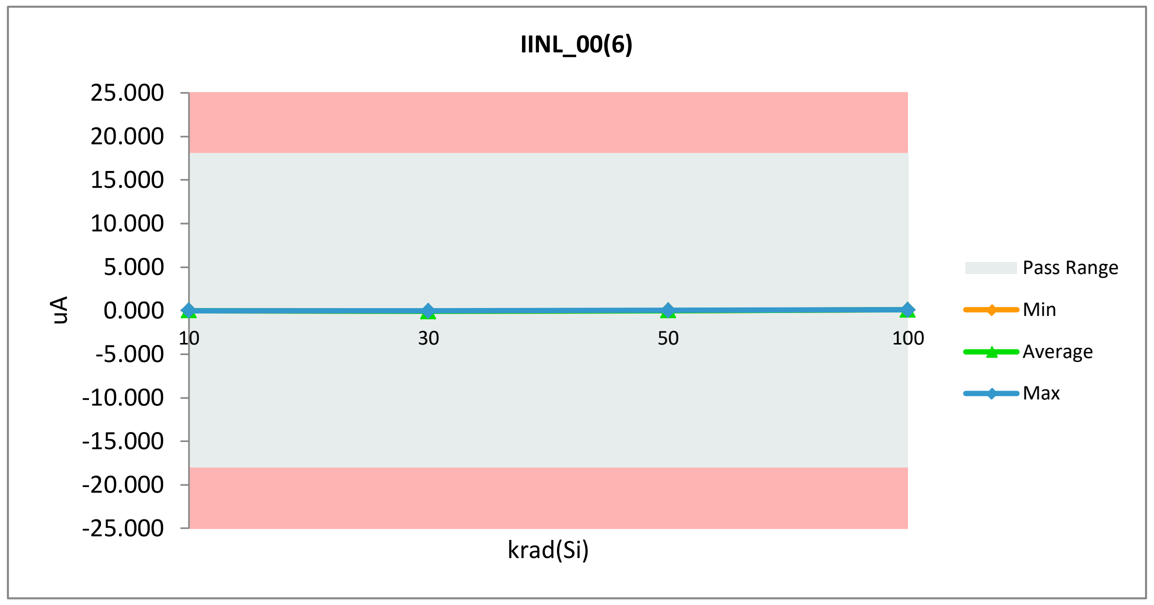
LDR UnBiased TID Report
SN55LVCP22A-SP

	IINL_00(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	18	18
Min Limit	-18	-18

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.028	-0.008	-0.021
10	7	-0.028	0.011	-0.039
10	8	-0.028	-0.008	-0.021
10	9	-0.009	0.011	-0.021
10	10	-0.028	0.011	-0.039
30	6	-0.028	-0.093	0.065
30	7	-0.028	-0.037	0.009
30	8	-0.028	-0.093	0.065
30	9	-0.009	-0.074	0.065
30	10	-0.028	-0.093	0.065
50	6	-0.028	0.008	-0.036
50	7	-0.028	0.008	-0.036
50	8	-0.028	0.008	-0.036
50	9	-0.009	0.027	-0.036
50	10	-0.028	0.008	-0.036
100	B011	-0.028	0.085	-0.113
100	B012	-0.028	0.085	-0.113
100	B013	-0.028	0.085	-0.113
100	B014	-0.028	0.085	-0.113
100	B015	-0.028	0.085	-0.113
	Max	-0.009	0.085	0.065
	Average	-0.025	0.006	-0.031
	Min	-0.028	-0.093	-0.113
	Std Dev	0.007	0.061	0.062

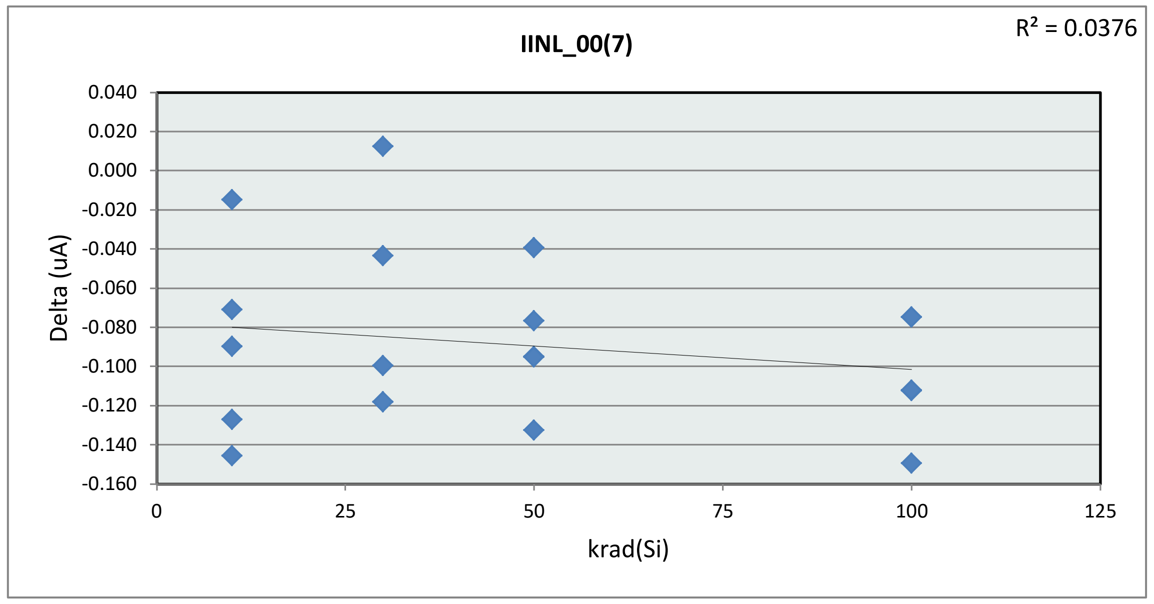


	IINL_00(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.008	-0.093	0.008	0.085
Average	0.004	-0.078	0.012	0.085
Max	0.011	-0.037	0.027	0.085
UL	18.000	18.000	18.000	18.000

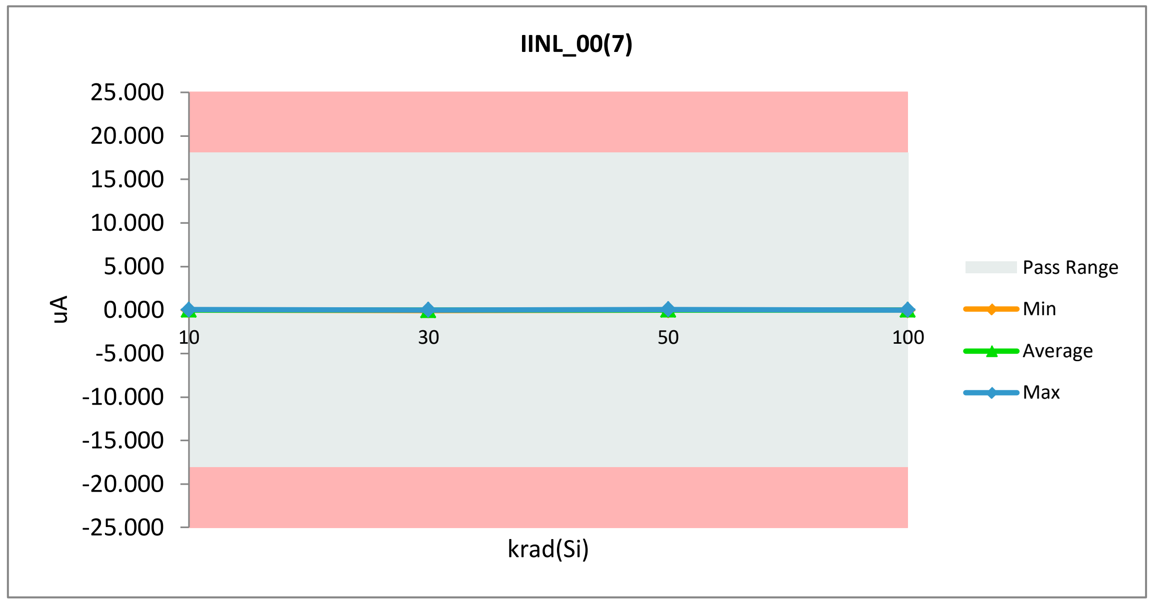


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_00(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.119	-0.030	-0.090
10	7	-0.045	-0.030	-0.015
10	8	-0.045	0.026	-0.071
10	9	-0.119	0.026	-0.146
10	10	-0.138	-0.011	-0.127
30	6	-0.119	-0.020	-0.099
30	7	-0.045	-0.001	-0.043
30	8	-0.045	-0.057	0.012
30	9	-0.119	-0.001	-0.118
30	10	-0.138	-0.020	-0.118
50	6	-0.119	-0.043	-0.077
50	7	-0.045	0.050	-0.095
50	8	-0.045	-0.005	-0.039
50	9	-0.119	-0.024	-0.095
50	10	-0.138	-0.005	-0.133
100	B011	-0.082	-0.007	-0.075
100	B012	-0.157	-0.007	-0.150
100	B013	-0.138	-0.026	-0.112
100	B014	-0.082	-0.007	-0.075
100	B015	-0.119	-0.007	-0.112
	Max	-0.045	0.050	0.012
	Average	-0.099	-0.010	-0.089
	Min	-0.157	-0.057	-0.150
	Std Dev	0.040	0.024	0.043

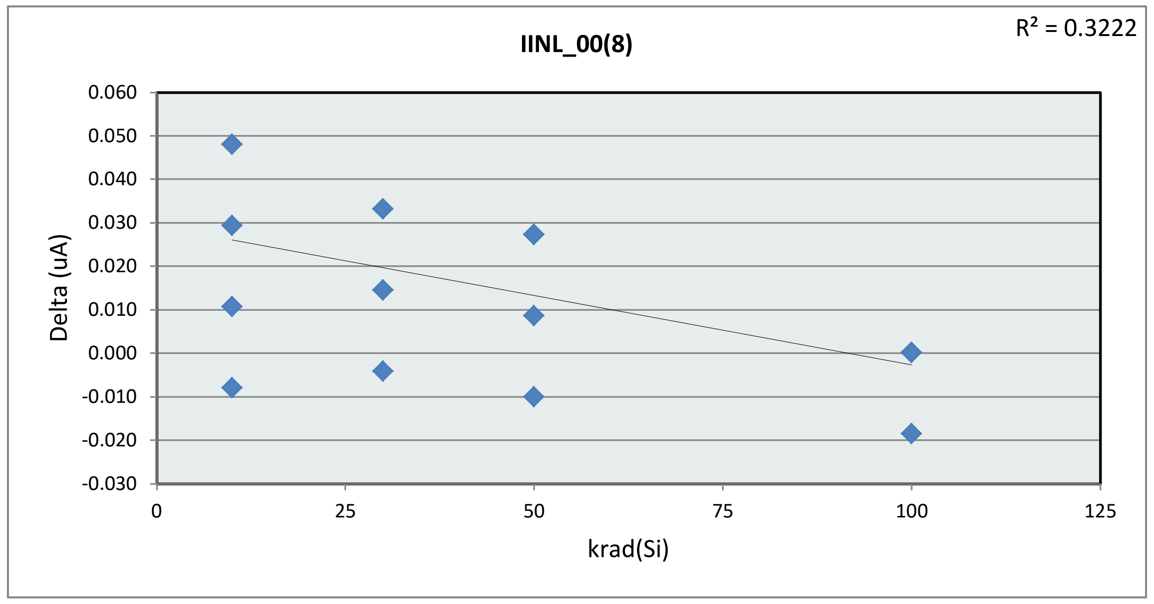


	IINL_00(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.030	-0.057	-0.043	-0.026
Average	-0.004	-0.020	-0.005	-0.011
Max	0.026	-0.001	0.050	-0.007
UL	18.000	18.000	18.000	18.000

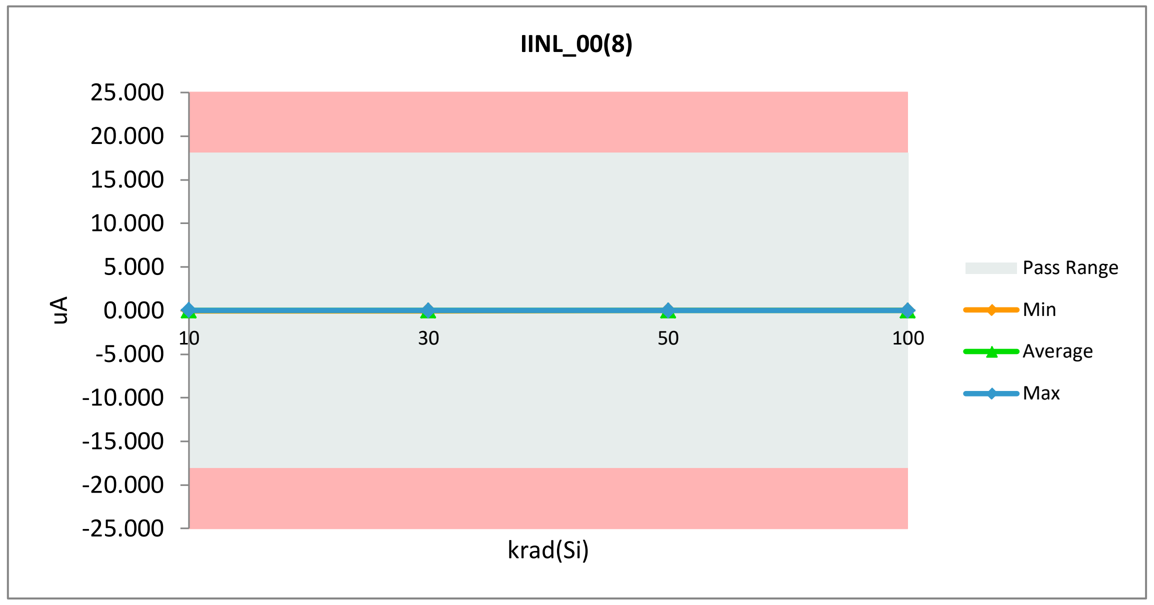


LDR UnBiased TID Report
SN55LVCP22A-SP

		IINL_00(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	18	18	
	Min Limit	-18	-18	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.004	-0.015	0.011
10	7	0.015	-0.033	0.048
10	8	0.015	-0.033	0.048
10	9	0.015	-0.015	0.029
10	10	0.015	0.023	-0.008
30	6	-0.004	0.000	-0.004
30	7	0.015	0.000	0.015
30	8	0.015	-0.018	0.033
30	9	0.015	0.000	0.015
30	10	0.015	-0.018	0.033
50	6	-0.004	0.006	-0.010
50	7	0.015	-0.012	0.027
50	8	0.015	-0.012	0.027
50	9	0.015	-0.012	0.027
50	10	0.015	0.006	0.009
100	B011	0.015	0.015	0.000
100	B012	-0.004	-0.004	0.000
100	B013	0.015	0.015	0.000
100	B014	0.015	0.015	0.000
100	B015	-0.004	0.015	-0.018
	Max	0.015	0.023	0.048
	Average	0.010	-0.004	0.014
	Min	-0.004	-0.033	-0.018
	Std Dev	0.008	0.016	0.019



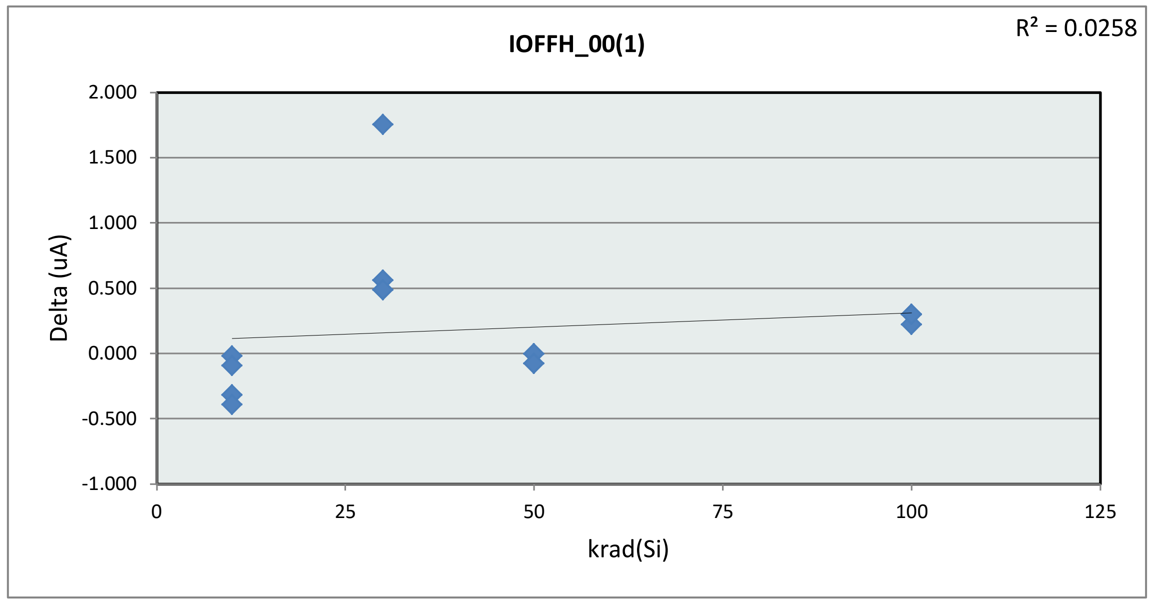
	IINL_00(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	18	uA		
Min Limit	-18	uA		
krad(Si)	10	30	50	100
LL	-18.000	-18.000	-18.000	-18.000
Min	-0.033	-0.018	-0.012	-0.004
Average	-0.015	-0.007	-0.005	0.011
Max	0.023	0.000	0.006	0.015
UL	18.000	18.000	18.000	18.000



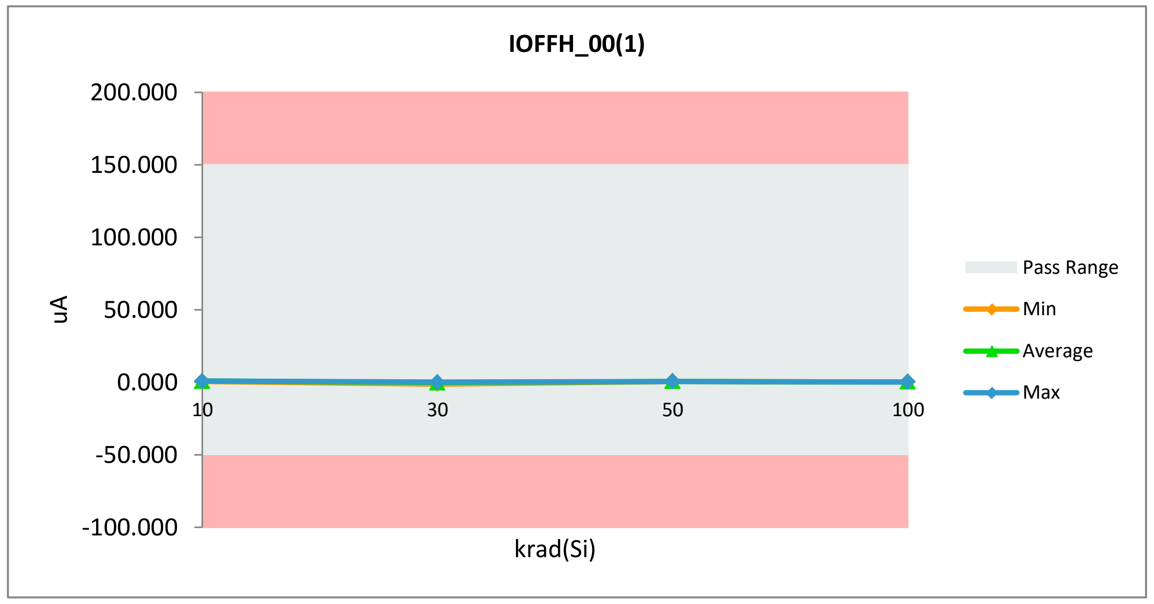
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFH_00(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	0.682	1.001	-0.319
10	7	0.682	1.001	-0.319
10	8	0.682	0.700	-0.018
10	9	0.607	0.700	-0.093
10	10	0.607	1.001	-0.393
30	6	0.682	0.121	0.561
30	7	0.682	0.121	0.561
30	8	0.682	-1.071	1.753
30	9	0.607	0.121	0.486
30	10	0.607	0.121	0.486
50	6	0.682	0.686	-0.004
50	7	0.682	0.686	-0.004
50	8	0.682	0.686	-0.004
50	9	0.607	0.686	-0.078
50	10	0.607	0.686	-0.078
100	B011	0.607	0.385	0.222
100	B012	0.682	0.385	0.297
100	B013	0.682	0.385	0.297
100	B014	0.682	0.385	0.297
100	B015	0.682	0.385	0.297
	Max	0.682	1.001	1.753
	Average	0.656	0.458	0.197
	Min	0.607	-1.071	-0.393
	Std Dev	0.036	0.463	0.469

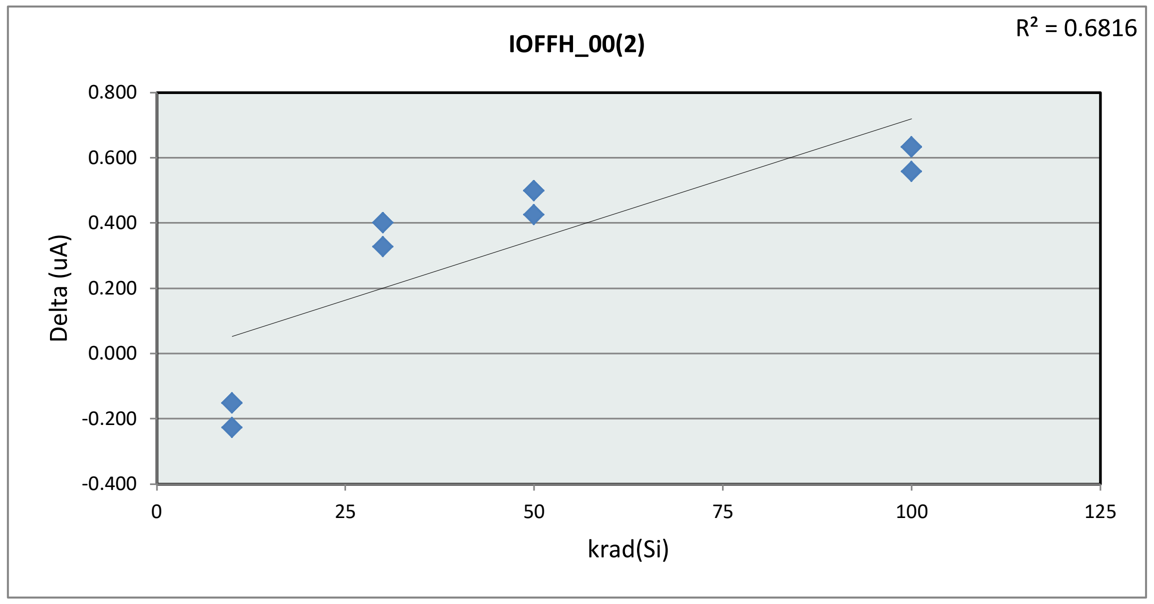


	IOFFH_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.700	-1.071	0.686	0.385
Average	0.881	-0.117	0.686	0.385
Max	1.001	0.121	0.686	0.385
UL	150.000	150.000	150.000	150.000

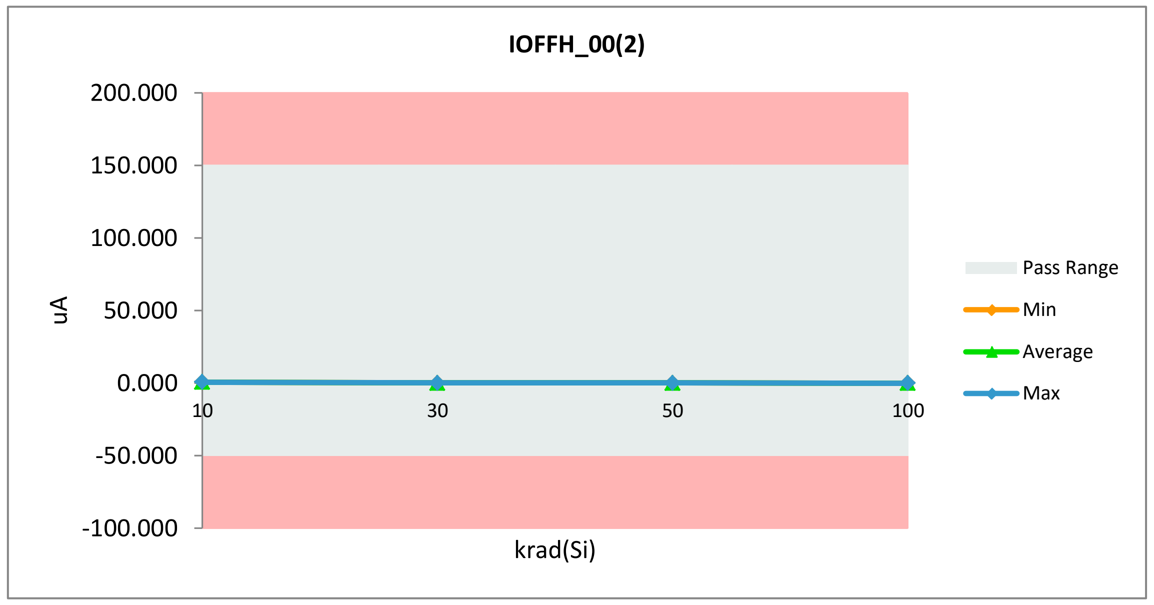


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_00(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.648	0.800	-0.152
10	7	0.648	0.800	-0.152
10	8	0.648	0.800	-0.152
10	9	0.574	0.800	-0.226
10	10	0.648	0.800	-0.152
30	6	0.648	0.248	0.401
30	7	0.648	0.248	0.401
30	8	0.648	0.248	0.401
30	9	0.574	0.248	0.326
30	10	0.648	0.248	0.401
50	6	0.648	0.149	0.499
50	7	0.648	0.149	0.499
50	8	0.648	0.149	0.499
50	9	0.574	0.149	0.424
50	10	0.648	0.149	0.499
100	B011	0.574	0.016	0.558
100	B012	0.648	0.016	0.632
100	B013	0.648	0.016	0.632
100	B014	0.648	0.016	0.632
100	B015	0.648	0.016	0.632
	Max	0.648	0.800	0.632
	Average	0.633	0.303	0.330
	Min	0.574	0.016	-0.226
	Std Dev	0.031	0.306	0.308

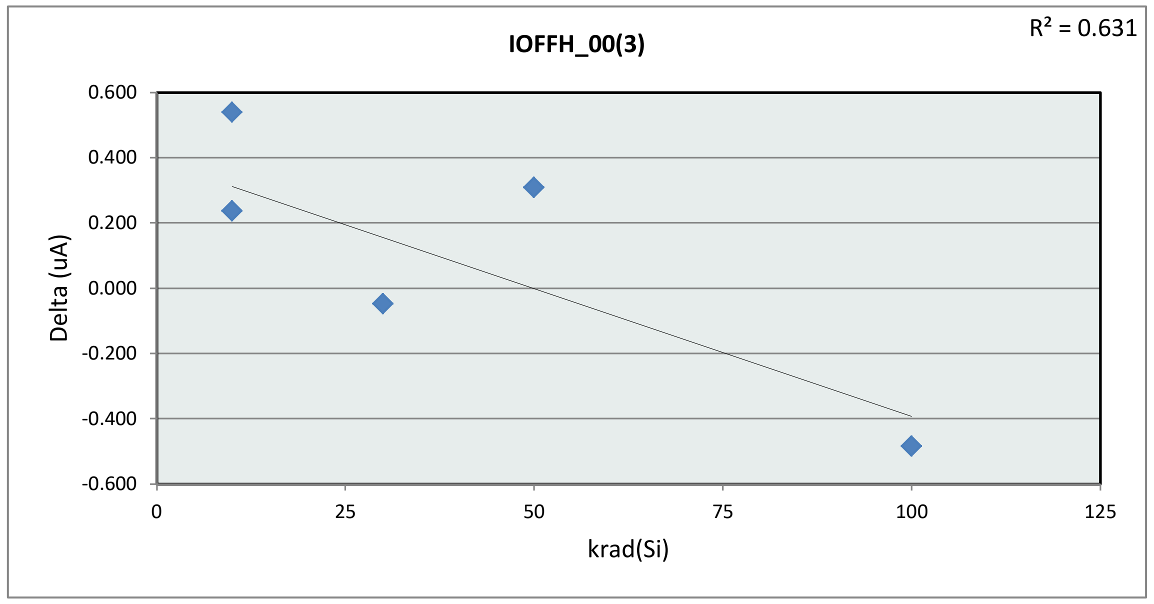


	IOFFH_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.800	0.248	0.149	0.016
Average	0.800	0.248	0.149	0.016
Max	0.800	0.248	0.149	0.016
UL	150.000	150.000	150.000	150.000

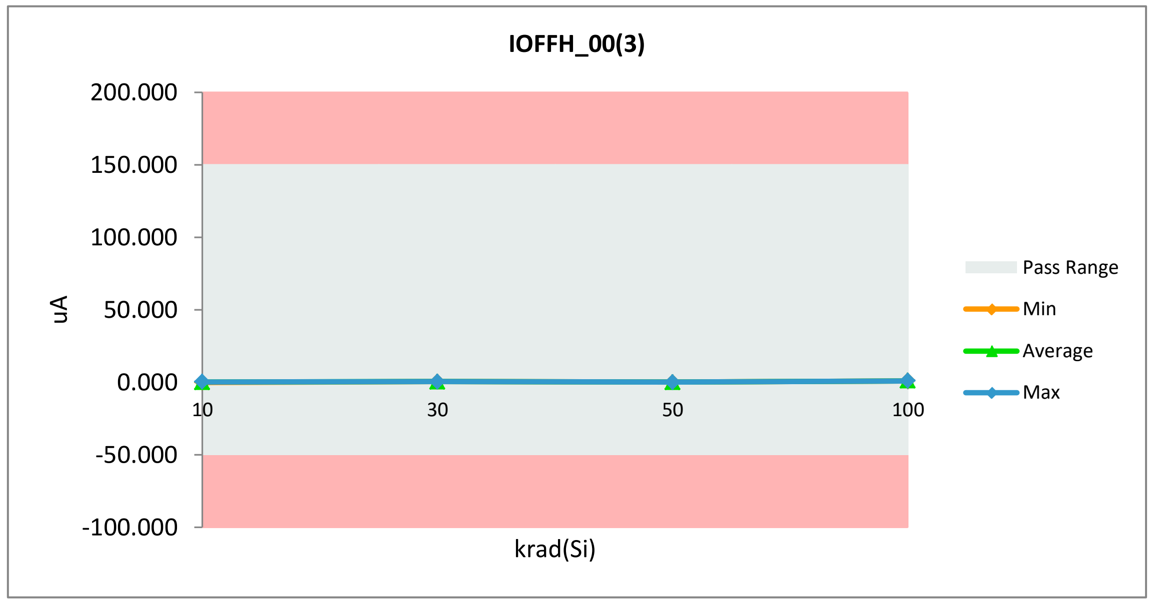


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_00(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.581	0.345	0.236
10	7	0.581	0.043	0.538
10	8	0.581	0.345	0.236
10	9	0.581	0.345	0.236
10	10	0.581	0.345	0.236
30	6	0.581	0.628	-0.047
30	7	0.581	0.628	-0.047
30	8	0.581	0.628	-0.047
30	9	0.581	0.628	-0.047
30	10	0.581	0.628	-0.047
50	6	0.581	0.273	0.308
50	7	0.581	0.273	0.308
50	8	0.581	0.273	0.308
50	9	0.581	0.273	0.308
50	10	0.581	0.273	0.308
100	B011	0.581	1.066	-0.485
100	B012	0.581	1.066	-0.485
100	B013	0.581	1.066	-0.485
100	B014	0.581	1.066	-0.485
100	B015	0.581	1.066	-0.485
	Max	0.581	1.066	0.538
	Average	0.581	0.563	0.018
	Min	0.581	0.043	-0.485
	Std Dev	0.000	0.338	0.338

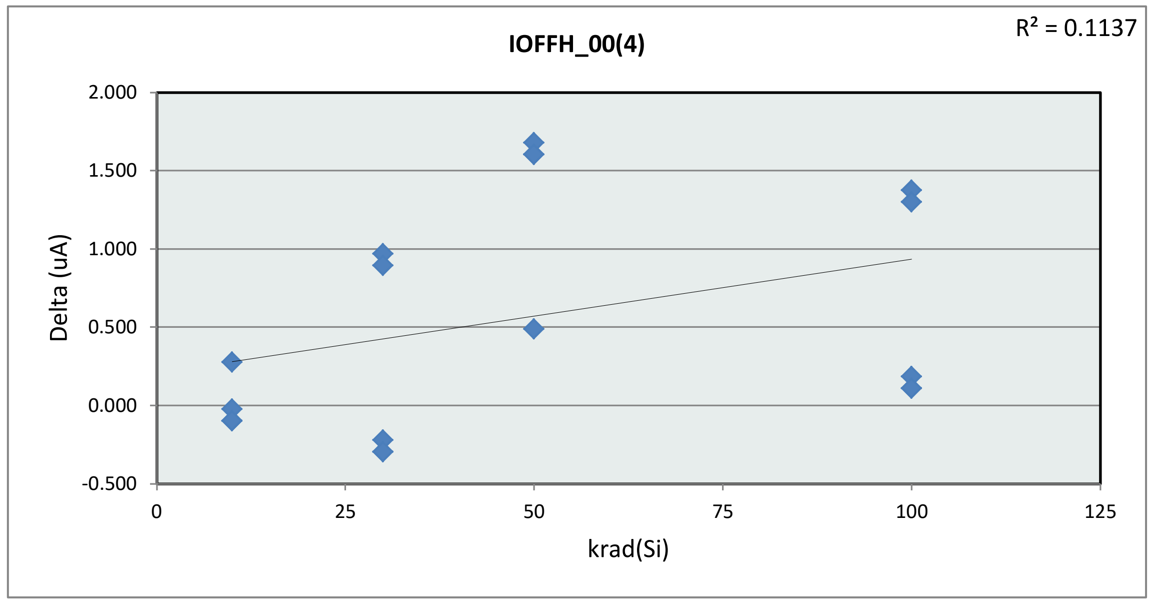


	IOFFH_00(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.043	0.628	0.273	1.066
Average	0.284	0.628	0.273	1.066
Max	0.345	0.628	0.273	1.066
UL	150.000	150.000	150.000	150.000

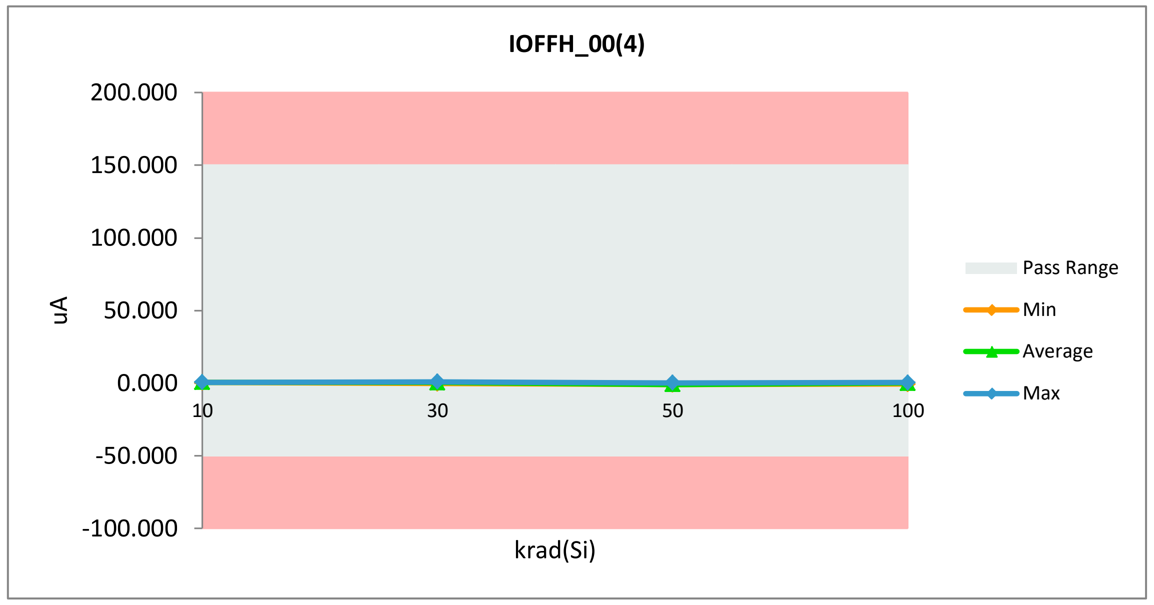


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_00(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	0.619	0.716	-0.097
10	7	0.694	0.416	0.278
10	8	0.694	0.716	-0.023
10	9	0.619	0.716	-0.097
10	10	0.619	0.716	-0.097
30	6	0.619	0.916	-0.297
30	7	0.694	-0.274	0.968
30	8	0.694	0.916	-0.223
30	9	0.619	0.916	-0.297
30	10	0.619	-0.274	0.893
50	6	0.619	-0.984	1.603
50	7	0.694	-0.984	1.678
50	8	0.694	0.207	0.487
50	9	0.619	-0.984	1.603
50	10	0.619	-0.984	1.603
100	B011	0.694	-0.682	1.376
100	B012	0.619	0.509	0.110
100	B013	0.619	-0.682	1.301
100	B014	0.694	0.509	0.185
100	B015	0.619	0.509	0.110
	Max	0.694	0.916	1.678
	Average	0.649	0.096	0.553
	Min	0.619	-0.984	-0.297
	Std Dev	0.037	0.737	0.738



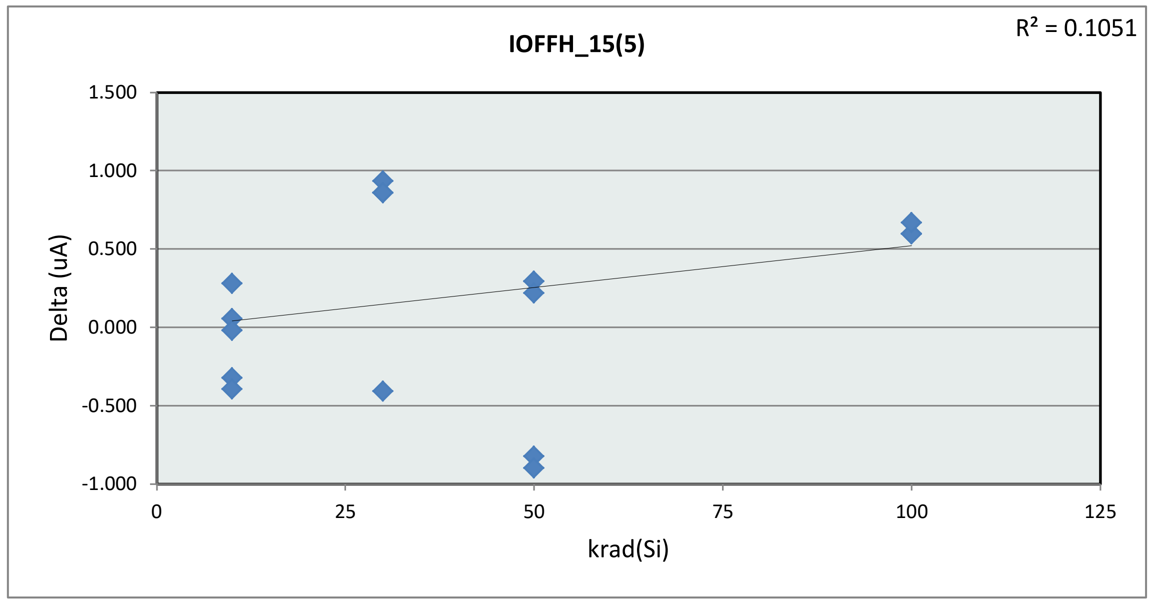
	IOFFH_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.416	-0.274	-0.984	-0.682
Average	0.656	0.440	-0.746	0.033
Max	0.716	0.916	0.207	0.509
UL	150.000	150.000	150.000	150.000



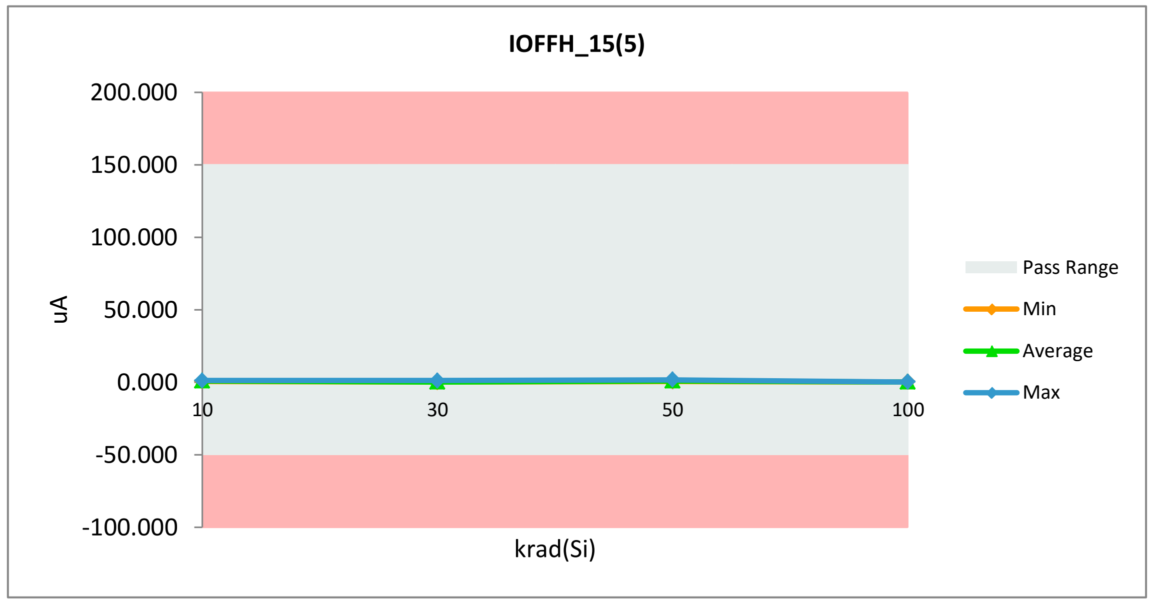
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFH_15(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbias	Delta
10	6	1.054	1.001	0.053
10	7	0.980	0.700	0.280
10	8	0.980	1.301	-0.322
10	9	0.905	1.301	-0.396
10	10	0.980	1.001	-0.021
30	6	1.054	0.121	0.933
30	7	0.980	0.121	0.859
30	8	0.980	0.121	0.859
30	9	0.905	1.313	-0.408
30	10	0.980	0.121	0.859
50	6	1.054	1.877	-0.823
50	7	0.980	0.686	0.294
50	8	0.980	0.686	0.294
50	9	0.905	0.686	0.220
50	10	0.980	1.877	-0.897
100	B011	0.980	0.385	0.595
100	B012	0.980	0.385	0.595
100	B013	0.980	0.385	0.595
100	B014	0.980	0.385	0.595
100	B015	1.054	0.385	0.669
	Max	1.054	1.877	0.933
	Average	0.983	0.742	0.242
	Min	0.905	0.121	-0.897
	Std Dev	0.045	0.555	0.561



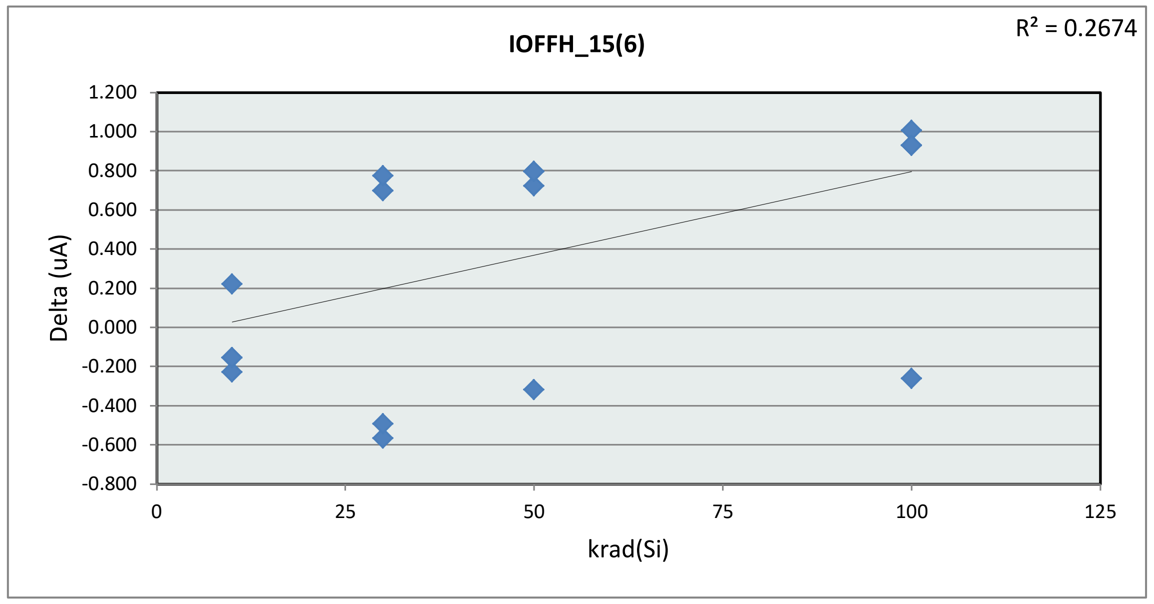
	IOFFH_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.700	0.121	0.686	0.385
Average	1.061	0.359	1.162	0.385
Max	1.301	1.313	1.877	0.385
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
SN55LVCP22A-SP

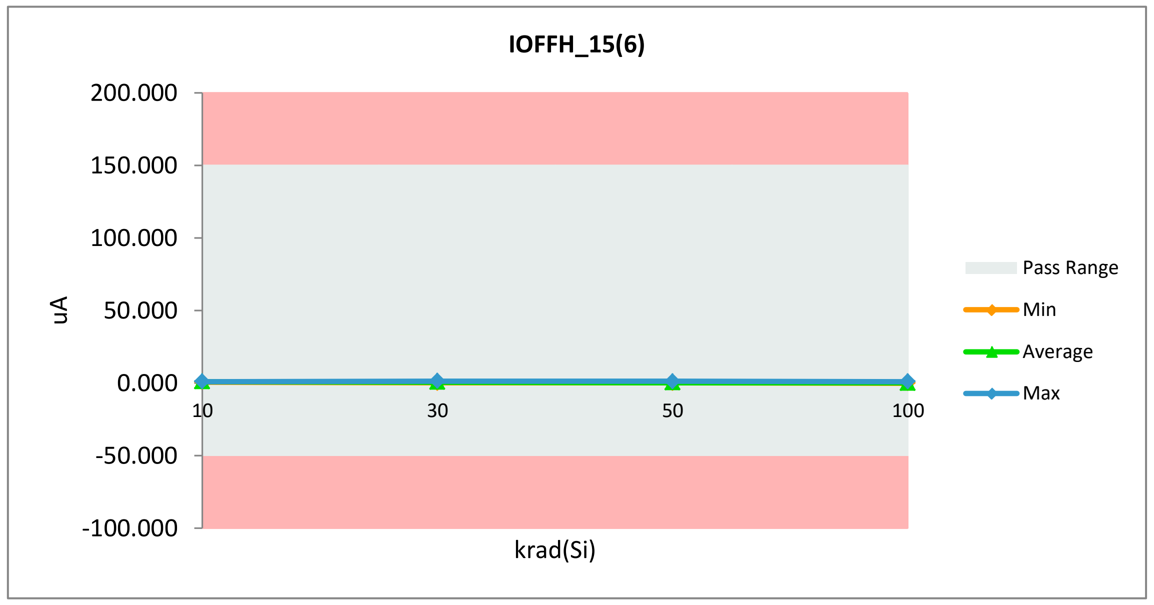
	IOFFH_15(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.946	1.101	-0.155
10	7	0.946	1.101	-0.155
10	8	1.021	0.800	0.221
10	9	0.872	1.101	-0.229
10	10	0.946	1.101	-0.155
30	6	0.946	0.248	0.698
30	7	0.946	0.248	0.698
30	8	1.021	0.248	0.773
30	9	0.872	1.439	-0.567
30	10	0.946	1.439	-0.493
50	6	0.946	0.149	0.797
50	7	0.946	0.149	0.797
50	8	1.021	1.340	-0.319
50	9	0.872	0.149	0.722
50	10	0.946	0.149	0.797
100	B011	0.946	0.016	0.930
100	B012	1.021	0.016	1.005
100	B013	0.946	1.207	-0.261
100	B014	0.946	0.016	0.930
100	B015	0.946	0.016	0.930
	Max	1.021	1.439	1.005
	Average	0.950	0.602	0.348
	Min	0.872	0.016	-0.567
	Std Dev	0.045	0.558	0.566



	IOFFH_15(6)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	uA
Min Limit	-50	uA

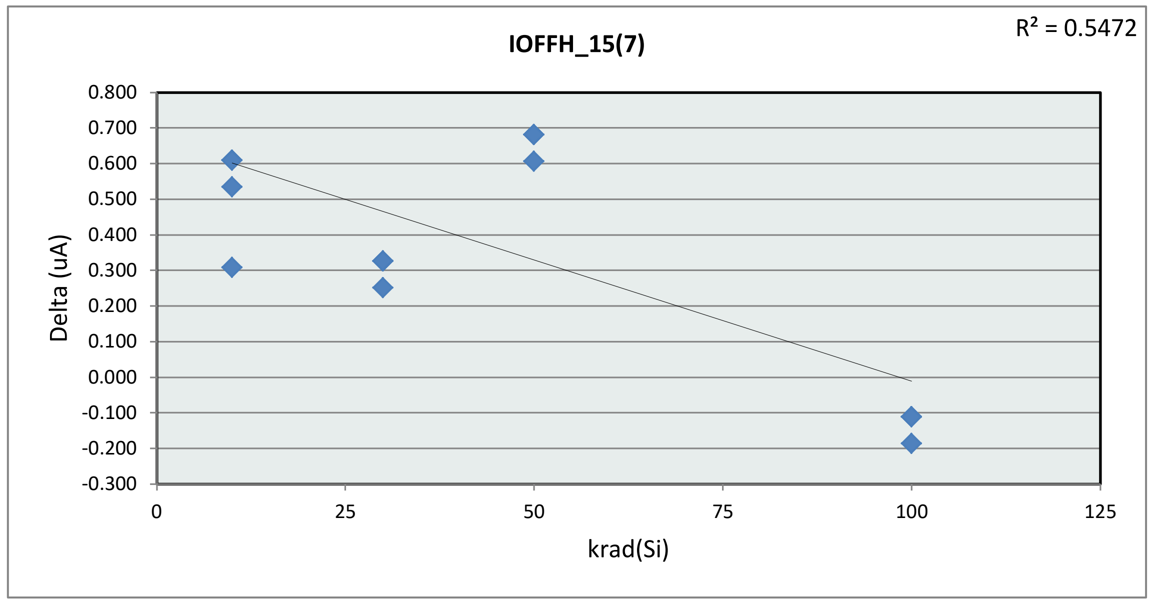
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.800	0.248	0.149	0.016
Average	1.041	0.724	0.388	0.254
Max	1.101	1.439	1.340	1.207
UL	150.000	150.000	150.000	150.000



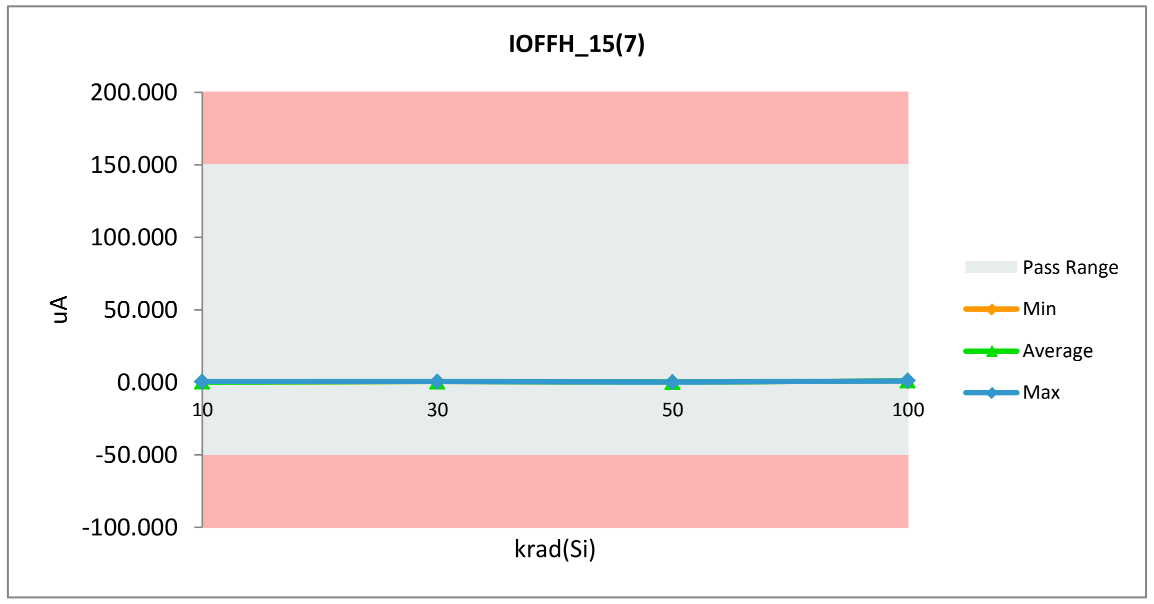
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFH_15(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	0.954	0.646	0.308
10	7	0.954	0.345	0.609
10	8	0.954	0.345	0.609
10	9	0.879	0.345	0.535
10	10	0.954	0.345	0.609
30	6	0.954	0.628	0.326
30	7	0.954	0.628	0.326
30	8	0.954	0.628	0.326
30	9	0.879	0.628	0.251
30	10	0.954	0.628	0.326
50	6	0.954	0.273	0.681
50	7	0.954	0.273	0.681
50	8	0.954	0.273	0.681
50	9	0.879	0.273	0.606
50	10	0.954	0.273	0.681
100	B011	0.879	1.066	-0.187
100	B012	0.954	1.066	-0.112
100	B013	0.954	1.066	-0.112
100	B014	0.954	1.066	-0.112
100	B015	0.954	1.066	-0.112
	Max	0.954	1.066	0.681
	Average	0.939	0.593	0.346
	Min	0.879	0.273	-0.187
	Std Dev	0.031	0.315	0.316

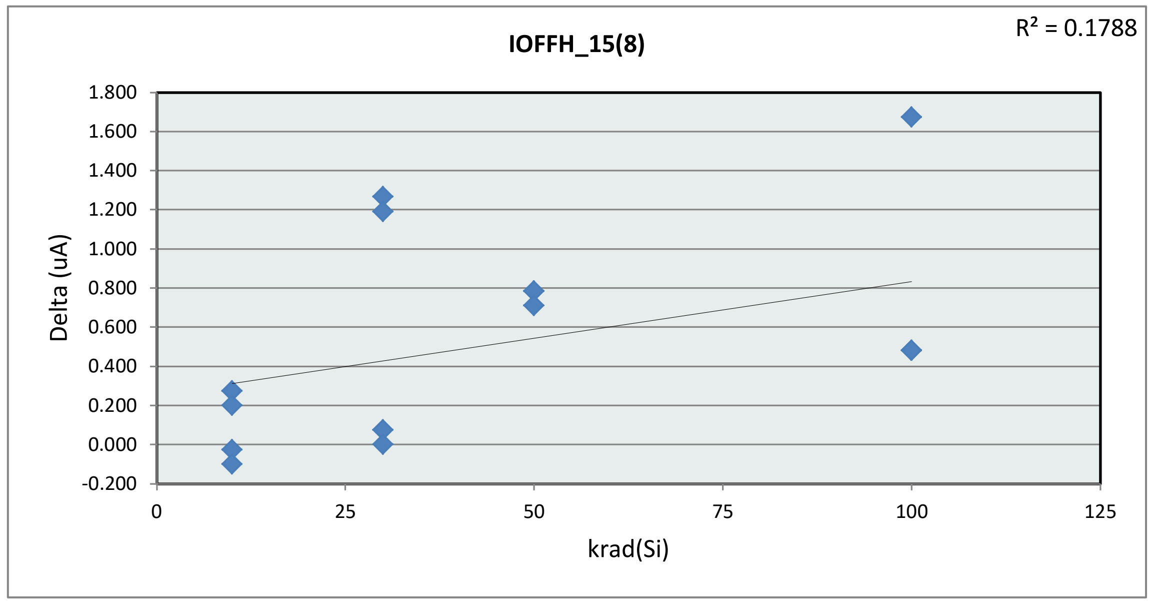


	IOFFH_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.345	0.628	0.273	1.066
Average	0.405	0.628	0.273	1.066
Max	0.646	0.628	0.273	1.066
UL	150.000	150.000	150.000	150.000

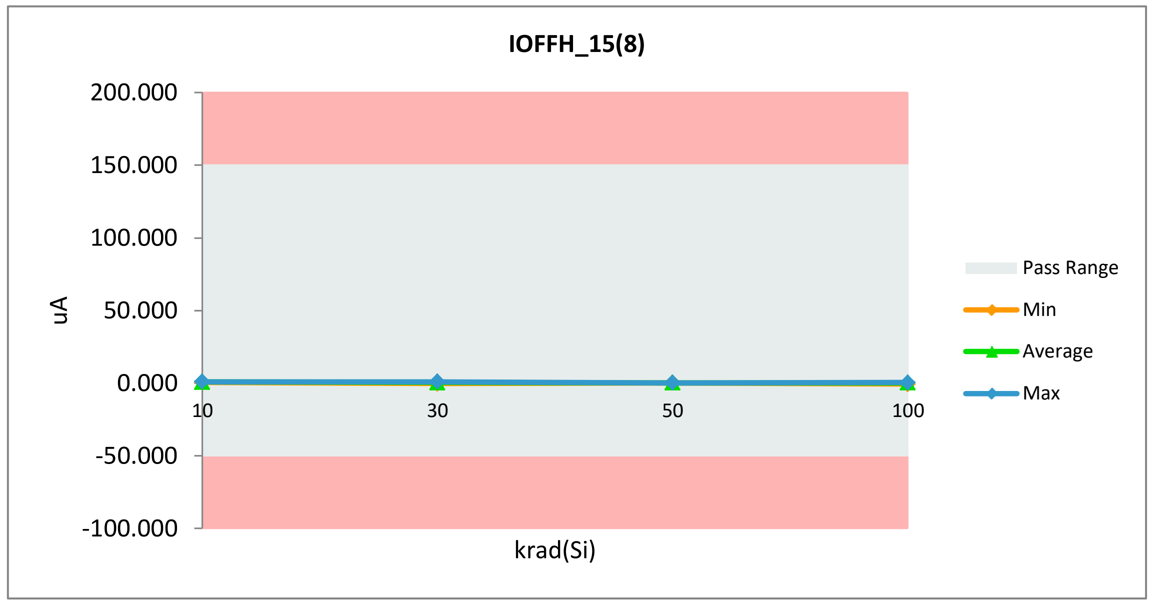


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFH_15(8)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.991	1.017	-0.025
10	7	0.991	0.716	0.275
10	8	0.991	0.716	0.275
10	9	0.917	1.017	-0.100
10	10	0.917	0.716	0.201
30	6	0.991	-0.274	1.266
30	7	0.991	0.916	0.075
30	8	0.991	0.916	0.075
30	9	0.917	-0.274	1.191
30	10	0.917	0.916	0.001
50	6	0.991	0.207	0.784
50	7	0.991	0.207	0.784
50	8	0.991	0.207	0.784
50	9	0.917	0.207	0.710
50	10	0.917	0.207	0.710
100	B011	0.991	-0.682	1.673
100	B012	0.991	0.509	0.482
100	B013	0.991	0.509	0.482
100	B014	0.991	0.509	0.482
100	B015	0.991	0.509	0.482
	Max	0.991	1.017	1.673
	Average	0.969	0.439	0.530
	Min	0.917	-0.682	-0.100
	Std Dev	0.035	0.467	0.470



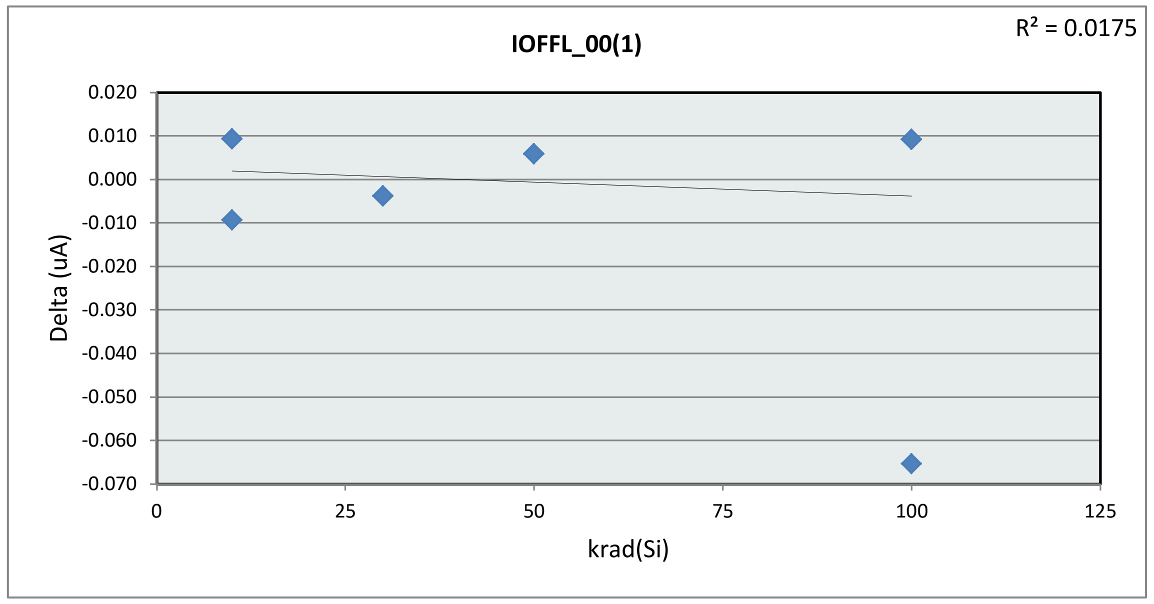
	IOFFH_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.716	-0.274	0.207	-0.682
Average	0.837	0.440	0.207	0.271
Max	1.017	0.916	0.207	0.509
UL	150.000	150.000	150.000	150.000



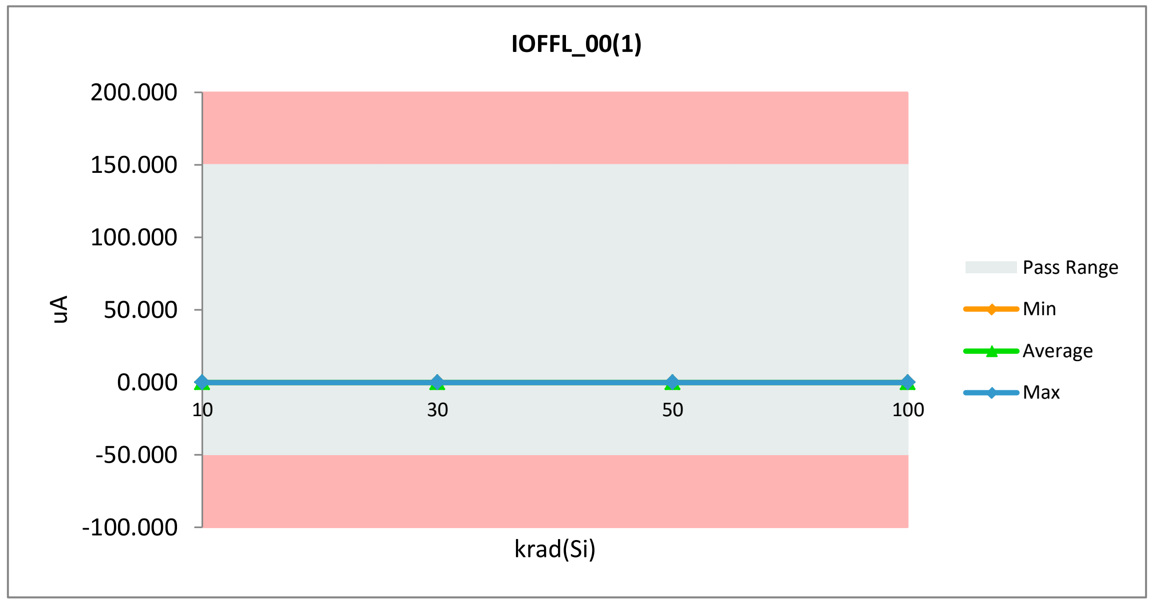
LDR UnBiased TID Report
SN55LVCP22A-SP

	IOFFL_00(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.012	0.002	0.009
10	7	0.012	0.002	0.009
10	8	0.012	0.021	-0.009
10	9	0.012	0.021	-0.009
10	10	0.012	0.002	0.009
30	6	0.012	0.016	-0.004
30	7	0.012	0.016	-0.004
30	8	0.012	0.016	-0.004
30	9	0.012	0.016	-0.004
30	10	0.012	0.016	-0.004
50	6	0.012	0.006	0.006
50	7	0.012	0.006	0.006
50	8	0.012	0.006	0.006
50	9	0.012	0.006	0.006
50	10	0.012	0.006	0.006
100	B011	0.012	0.003	0.009
100	B012	0.012	0.003	0.009
100	B013	-0.063	0.003	-0.065
100	B014	0.012	0.003	0.009
100	B015	0.012	0.003	0.009
	Max	0.012	0.021	0.009
	Average	0.008	0.008	0.000
	Min	-0.063	0.002	-0.065
	Std Dev	0.017	0.007	0.017

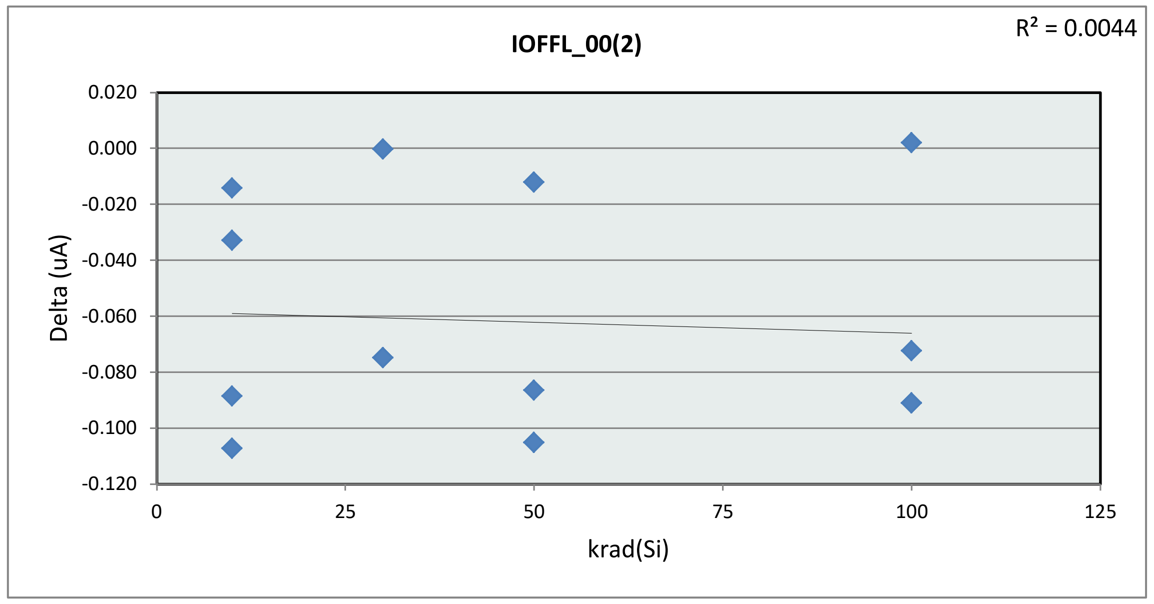


	IOFFL_00(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.002	0.016	0.006	0.003
Average	0.010	0.016	0.006	0.003
Max	0.021	0.016	0.006	0.003
UL	150.000	150.000	150.000	150.000

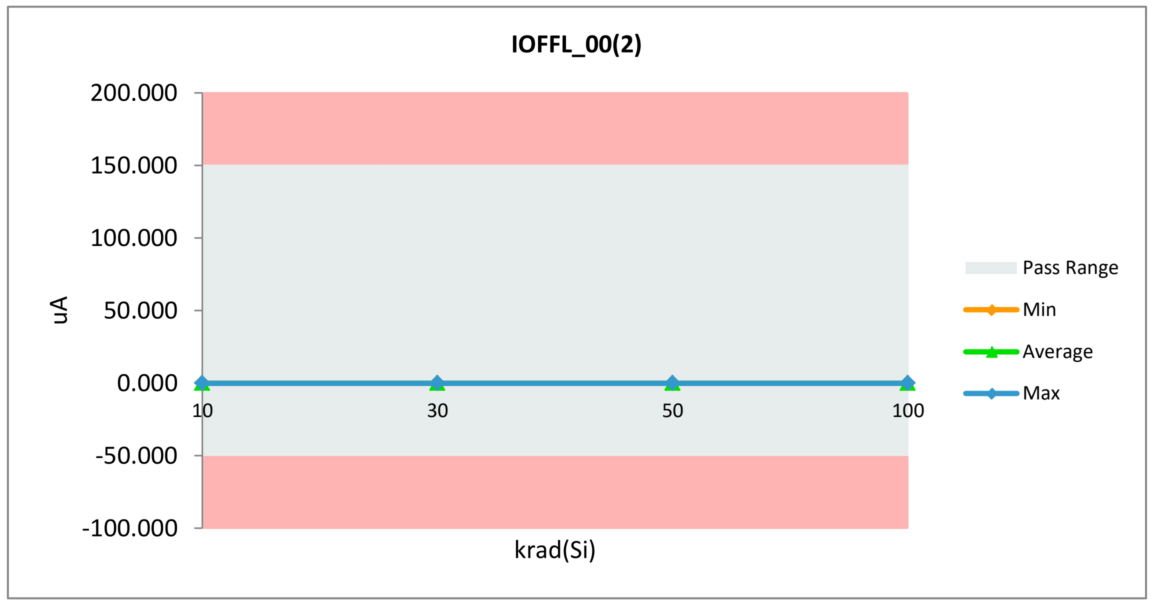


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.096	-0.008	-0.089
10	7	-0.096	0.011	-0.107
10	8	-0.096	0.011	-0.107
10	9	-0.022	-0.008	-0.014
10	10	-0.022	0.011	-0.033
30	6	-0.096	-0.022	-0.075
30	7	-0.096	-0.022	-0.075
30	8	-0.096	-0.022	-0.075
30	9	-0.022	-0.022	0.000
30	10	-0.022	-0.022	0.000
50	6	-0.096	0.009	-0.105
50	7	-0.096	0.009	-0.105
50	8	-0.096	-0.010	-0.087
50	9	-0.022	-0.010	-0.012
50	10	-0.022	-0.010	-0.012
100	B011	-0.096	-0.005	-0.091
100	B012	-0.096	-0.005	-0.091
100	B013	-0.022	-0.024	0.002
100	B014	-0.096	-0.005	-0.091
100	B015	-0.096	-0.024	-0.072
	Max	-0.022	0.011	0.002
	Average	-0.070	-0.008	-0.062
	Min	-0.096	-0.024	-0.107
	Std Dev	0.036	0.013	0.041



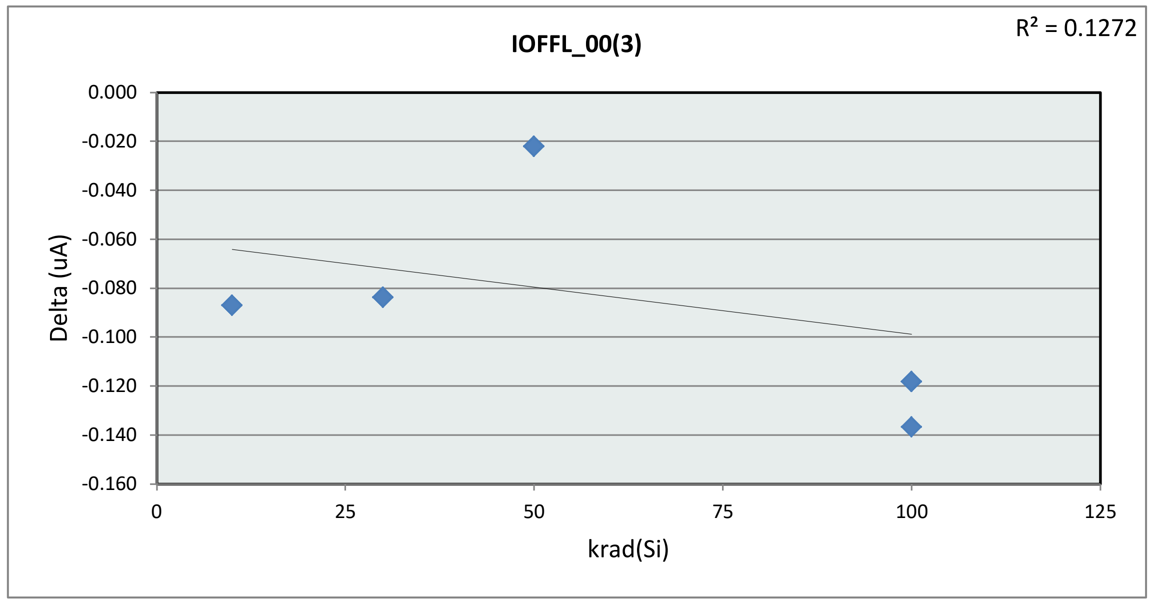
	IOFFL_00(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.008	-0.022	-0.010	-0.024
Average	0.004	-0.022	-0.002	-0.013
Max	0.011	-0.022	0.009	-0.005
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
SN55LVCP22A-SP

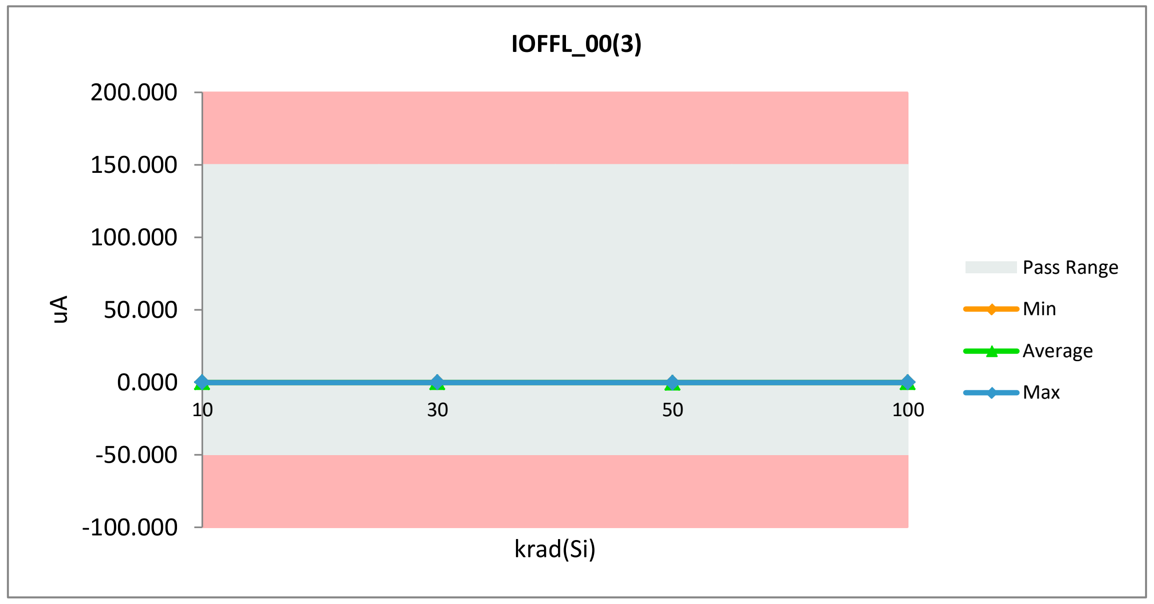
	IOFFL_00(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-0.090	-0.003	-0.087
10	7	-0.090	-0.003	-0.087
10	8	-0.090	-0.003	-0.087
10	9	-0.090	-0.003	-0.087
10	10	-0.090	-0.003	-0.087
30	6	-0.090	-0.006	-0.084
30	7	-0.090	-0.006	-0.084
30	8	-0.090	-0.006	-0.084
30	9	-0.090	-0.006	-0.084
30	10	-0.090	-0.006	-0.084
50	6	-0.090	-0.068	-0.022
50	7	-0.090	-0.068	-0.022
50	8	-0.090	-0.068	-0.022
50	9	-0.090	-0.068	-0.022
50	10	-0.090	-0.068	-0.022
100	B011	-0.090	0.028	-0.118
100	B012	-0.090	0.028	-0.118
100	B013	-0.090	0.028	-0.118
100	B014	-0.090	0.028	-0.118
100	B015	-0.090	0.047	-0.137
	Max	-0.090	0.047	-0.022
	Average	-0.090	-0.011	-0.079
	Min	-0.090	-0.068	-0.137
	Std Dev	0.000	0.037	0.037



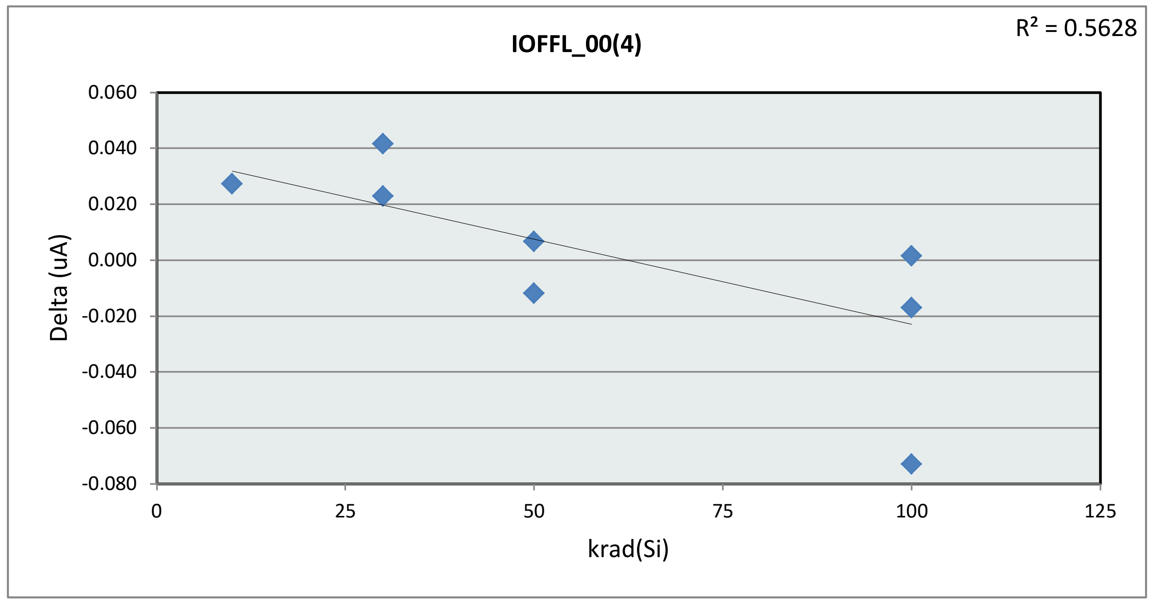
	IOFFL_00(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	150	uA
Min Limit	-50	uA

krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.003	-0.006	-0.068	0.028
Average	-0.003	-0.006	-0.068	0.032
Max	-0.003	-0.006	-0.068	0.047
UL	150.000	150.000	150.000	150.000

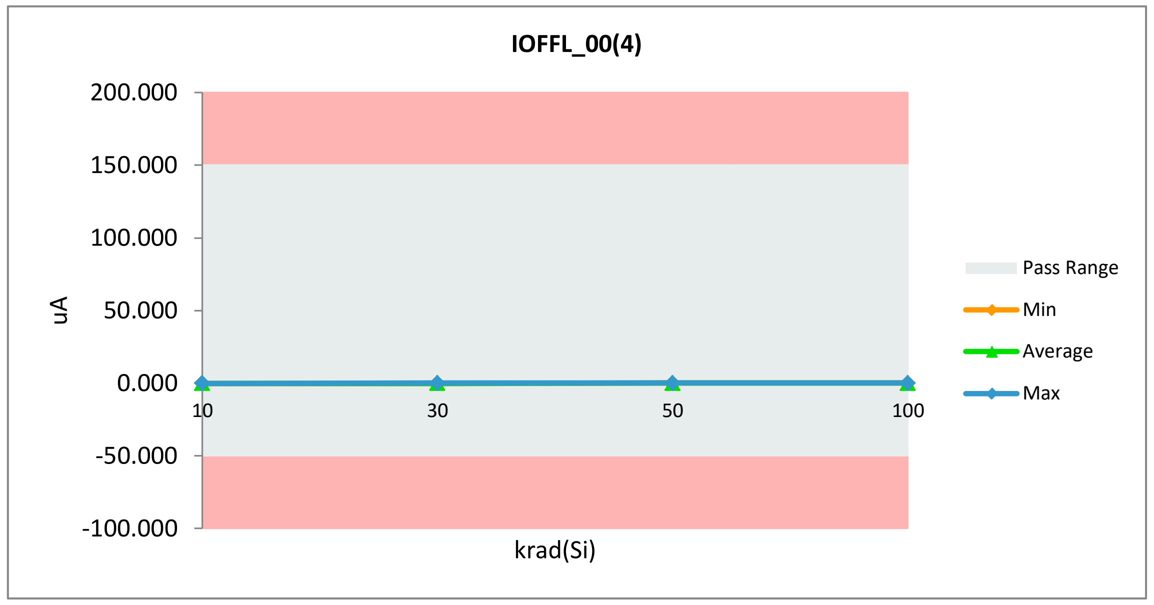


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_00(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		uA	uA	
Max Limit		150	150	
Min Limit		-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.024	-0.003	0.027
10	7	0.024	-0.003	0.027
10	8	0.024	-0.003	0.027
10	9	0.024	-0.003	0.027
10	10	0.024	-0.003	0.027
30	6	0.024	-0.018	0.042
30	7	0.024	0.001	0.023
30	8	0.024	0.001	0.023
30	9	0.024	-0.018	0.042
30	10	0.024	-0.018	0.042
50	6	0.024	0.036	-0.012
50	7	0.024	0.036	-0.012
50	8	0.024	0.017	0.007
50	9	0.024	0.017	0.007
50	10	0.024	0.036	-0.012
100	B011	0.024	0.022	0.001
100	B012	0.024	0.022	0.001
100	B013	0.024	0.041	-0.017
100	B014	-0.051	0.022	-0.073
100	B015	0.024	0.041	-0.017
	Max	0.024	0.041	0.042
	Average	0.020	0.011	0.009
	Min	-0.051	-0.018	-0.073
	Std Dev	0.017	0.020	0.028

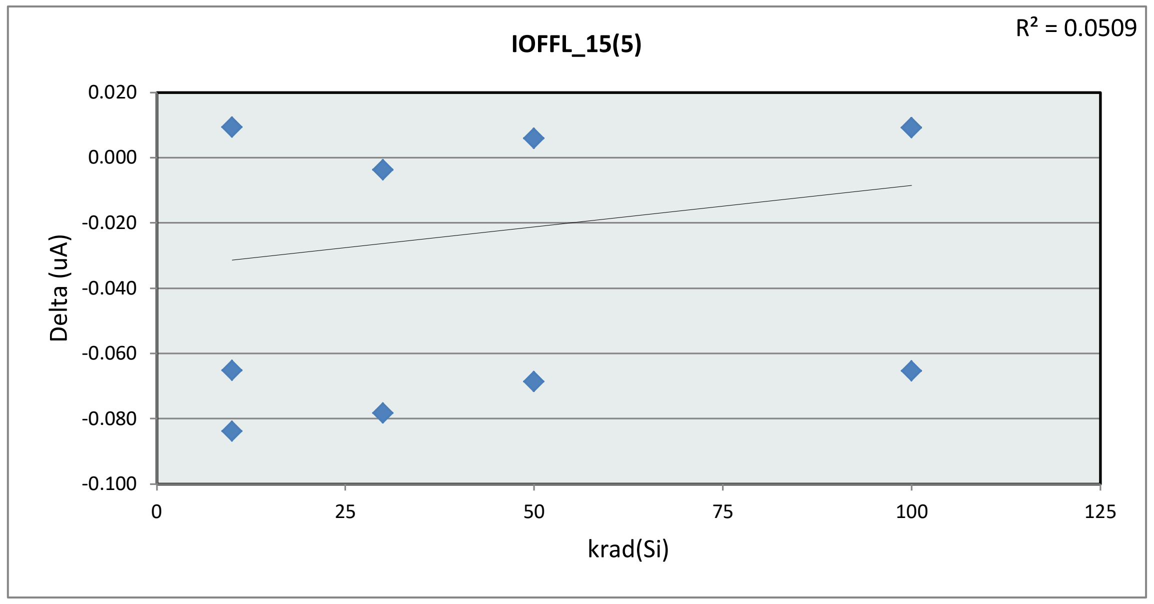


	IOFFL_00(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.003	-0.018	0.017	0.022
Average	-0.003	-0.010	0.028	0.030
Max	-0.003	0.001	0.036	0.041
UL	150.000	150.000	150.000	150.000

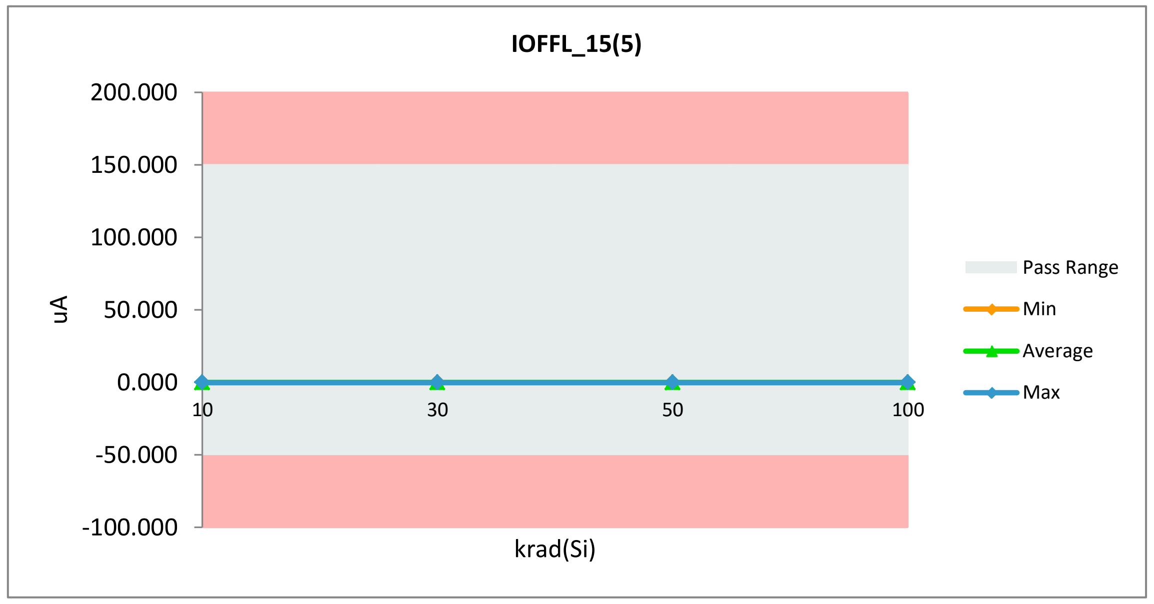


LDR UnBiased TID Report
SN55LVCP22A-SP

		IOFFL_15(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.012	0.002	0.009
10	7	0.012	0.002	0.009
10	8	-0.063	0.002	-0.065
10	9	-0.063	0.021	-0.084
10	10	0.012	0.002	0.009
30	6	0.012	0.016	-0.004
30	7	0.012	0.016	-0.004
30	8	-0.063	0.016	-0.078
30	9	-0.063	0.016	-0.078
30	10	0.012	0.016	-0.004
50	6	0.012	0.006	0.006
50	7	0.012	0.006	0.006
50	8	-0.063	0.006	-0.069
50	9	-0.063	0.006	-0.069
50	10	0.012	0.006	0.006
100	B011	0.012	0.003	0.009
100	B012	-0.063	0.003	-0.065
100	B013	0.012	0.003	0.009
100	B014	0.012	0.003	0.009
100	B015	0.012	0.003	0.009
	Max	0.012	0.021	0.009
	Average	-0.014	0.008	-0.022
	Min	-0.063	0.002	-0.084
	Std Dev	0.036	0.006	0.039



	IOFFL_15(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	0.002	0.016	0.006	0.003
Average	0.006	0.016	0.006	0.003
Max	0.021	0.016	0.006	0.003
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
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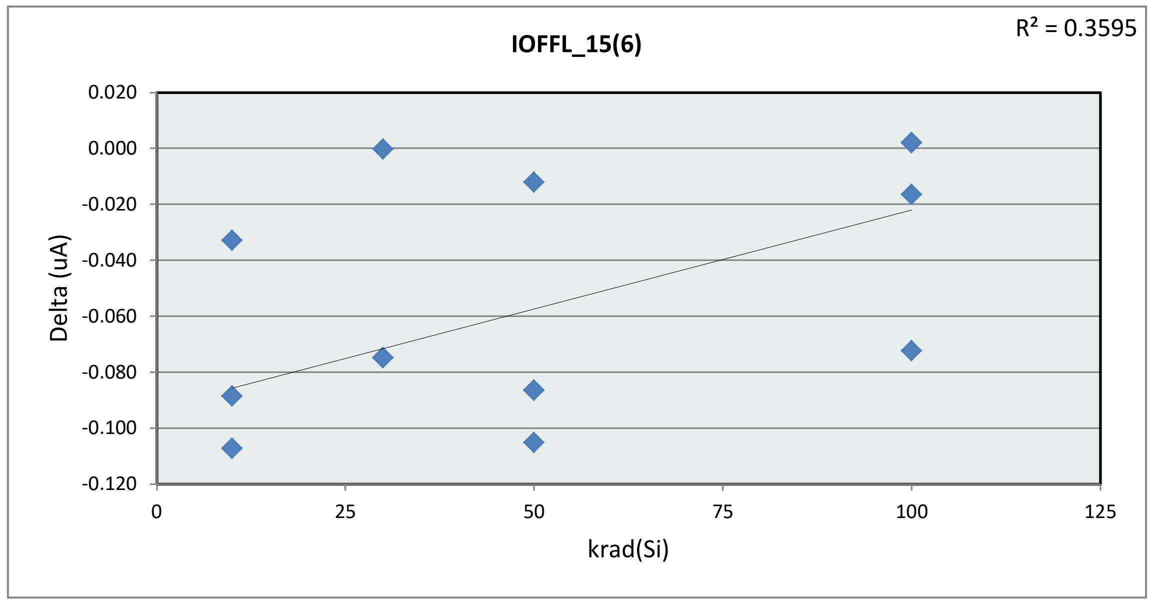
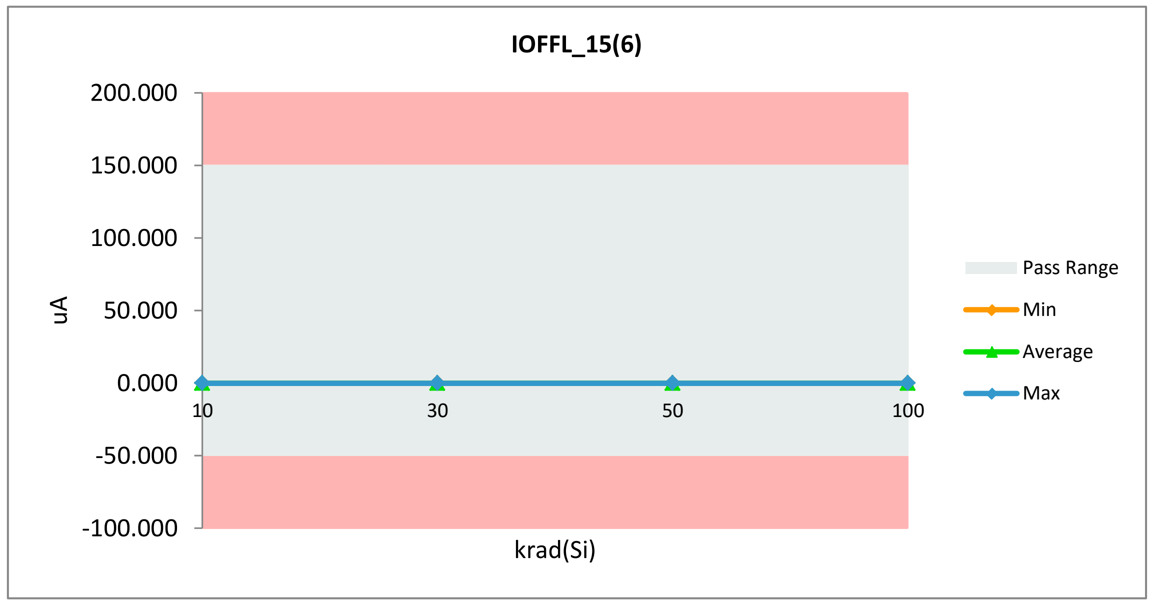
		IOFFL_15(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.022	0.011	-0.033
10	7	-0.096	-0.008	-0.089
10	8	-0.096	0.011	-0.107
10	9	-0.096	0.011	-0.107
10	10	-0.096	-0.008	-0.089
30	6	-0.022	-0.022	0.000
30	7	-0.096	-0.022	-0.075
30	8	-0.096	-0.022	-0.075
30	9	-0.096	-0.022	-0.075
30	10	-0.096	-0.022	-0.075
50	6	-0.022	-0.010	-0.012
50	7	-0.096	-0.010	-0.087
50	8	-0.096	-0.010	-0.087
50	9	-0.096	-0.010	-0.087
50	10	-0.096	0.009	-0.105
100	B011	-0.022	-0.024	0.002
100	B012	-0.096	-0.024	-0.072
100	B013	-0.022	-0.024	0.002
100	B014	-0.022	-0.024	0.002
100	B015	-0.022	-0.005	-0.017
	Max	-0.022	0.011	0.002
	Average	-0.070	-0.011	-0.059
	Min	-0.096	-0.024	-0.107
	Std Dev	0.036	0.013	0.041



	IOFFL_15(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.008	-0.022	-0.010	-0.024
Average	0.004	-0.022	-0.006	-0.020
Max	0.011	-0.022	0.009	-0.005
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
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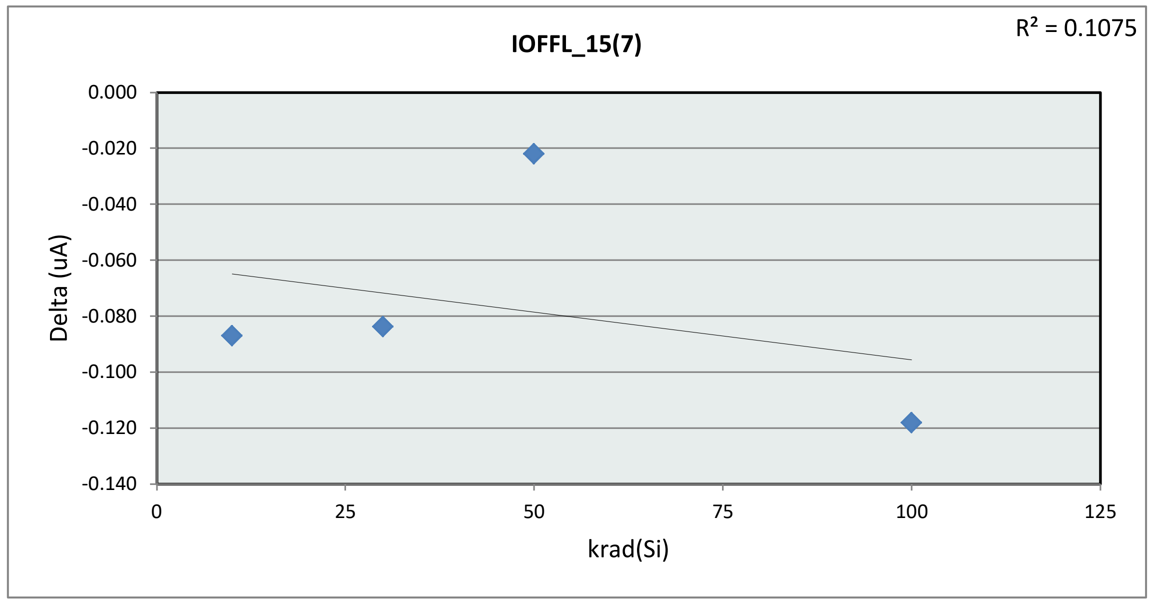
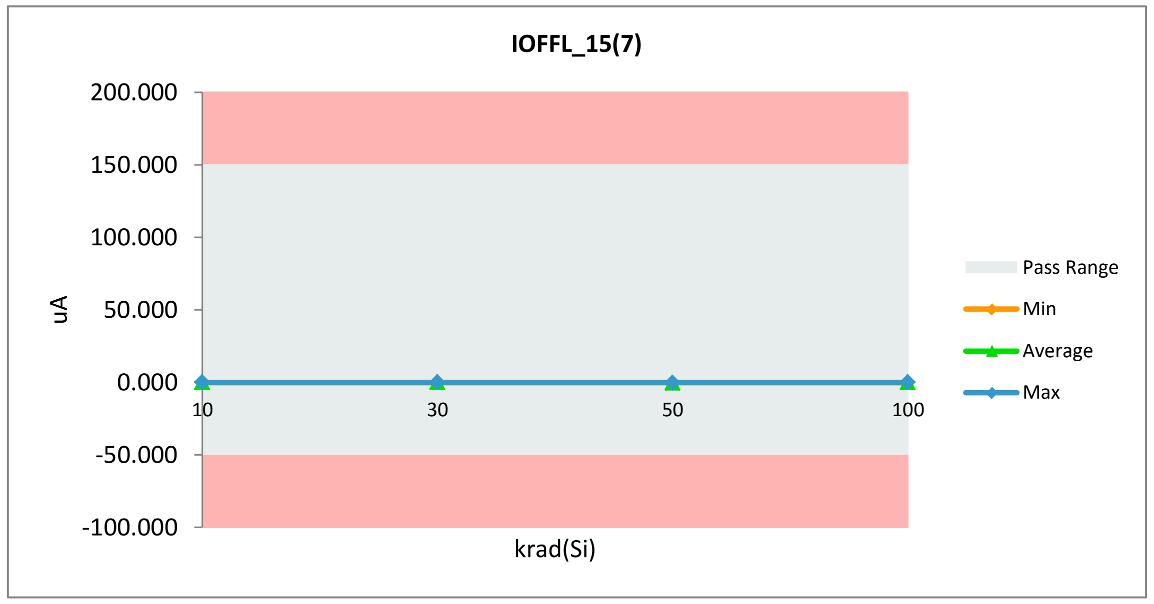
		IOFFL_15(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	-50	-50	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.090	-0.003	-0.087
10	7	-0.090	-0.003	-0.087
10	8	-0.090	-0.003	-0.087
10	9	-0.090	-0.003	-0.087
10	10	-0.090	-0.003	-0.087
30	6	-0.090	-0.006	-0.084
30	7	-0.090	-0.006	-0.084
30	8	-0.090	-0.006	-0.084
30	9	-0.090	-0.006	-0.084
30	10	-0.090	-0.006	-0.084
50	6	-0.090	-0.068	-0.022
50	7	-0.090	-0.068	-0.022
50	8	-0.090	-0.068	-0.022
50	9	-0.090	-0.068	-0.022
50	10	-0.090	-0.068	-0.022
100	B011	-0.090	0.028	-0.118
100	B012	-0.090	0.028	-0.118
100	B013	-0.090	0.028	-0.118
100	B014	-0.090	0.028	-0.118
100	B015	-0.090	0.028	-0.118
	Max	-0.090	0.028	-0.022
	Average	-0.090	-0.012	-0.078
	Min	-0.090	-0.068	-0.118
	Std Dev	0.000	0.036	0.036



	IOFFL_15(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.003	-0.006	-0.068	0.028
Average	-0.003	-0.006	-0.068	0.028
Max	-0.003	-0.006	-0.068	0.028
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
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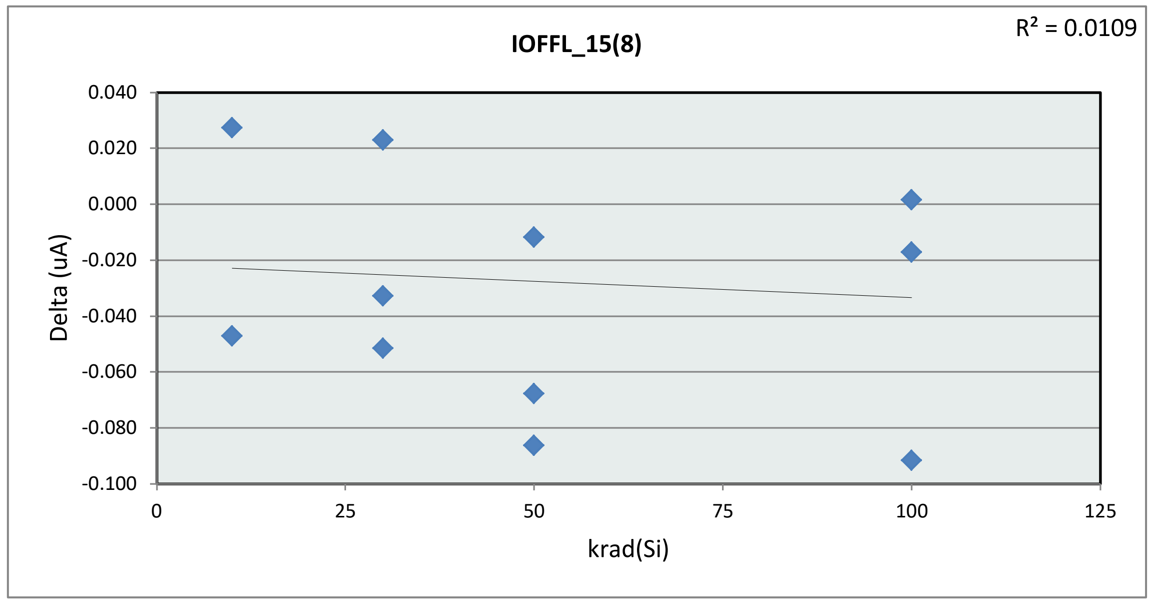
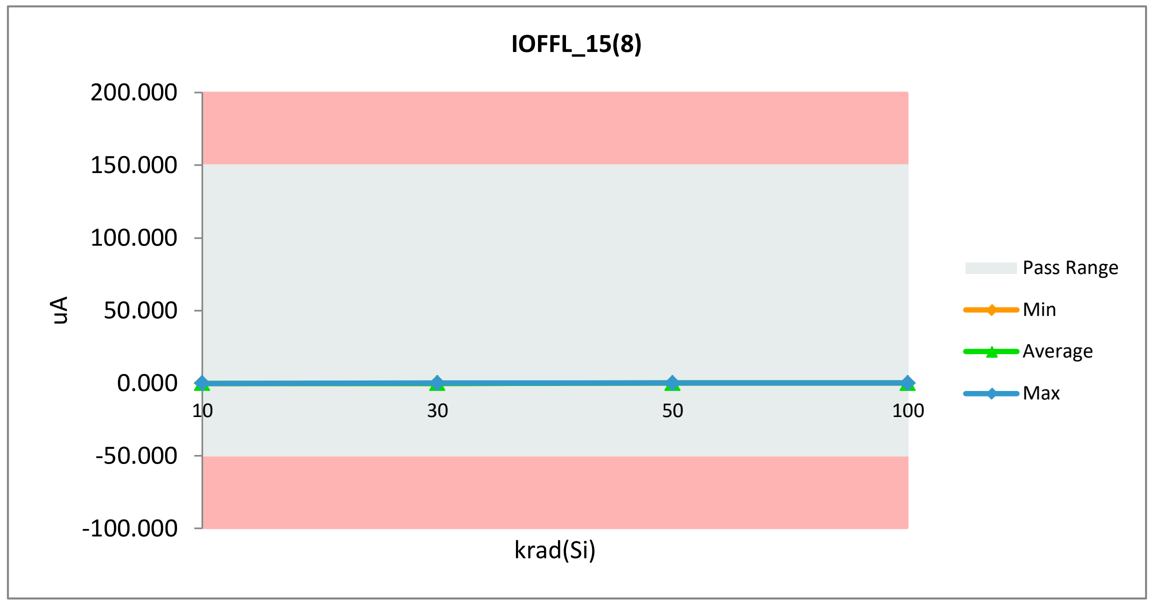
	IOFFL_15(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	uA	uA
Max Limit	150	150
Min Limit	-50	-50

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-0.051	-0.003	-0.047
10	7	0.024	-0.003	0.027
10	8	-0.051	-0.003	-0.047
10	9	-0.051	-0.003	-0.047
10	10	0.024	-0.003	0.027
30	6	-0.051	-0.018	-0.033
30	7	0.024	0.001	0.023
30	8	-0.051	0.001	-0.052
30	9	-0.051	-0.018	-0.033
30	10	0.024	0.001	0.023
50	6	-0.051	0.036	-0.086
50	7	0.024	0.036	-0.012
50	8	-0.051	0.017	-0.068
50	9	-0.051	0.036	-0.086
50	10	0.024	0.036	-0.012
100	B011	0.024	0.041	-0.017
100	B012	0.024	0.022	0.001
100	B013	0.024	0.041	-0.017
100	B014	0.024	0.022	0.001
100	B015	-0.051	0.041	-0.092
	Max	0.024	0.041	0.027
	Average	-0.013	0.014	-0.027
	Min	-0.051	-0.018	-0.092
	Std Dev	0.038	0.021	0.038



	IOFFL_15(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	uA		
Min Limit	-50	uA		
krad(Si)	10	30	50	100
LL	-50.000	-50.000	-50.000	-50.000
Min	-0.003	-0.018	0.017	0.022
Average	-0.003	-0.006	0.032	0.034
Max	-0.003	0.001	0.036	0.041
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
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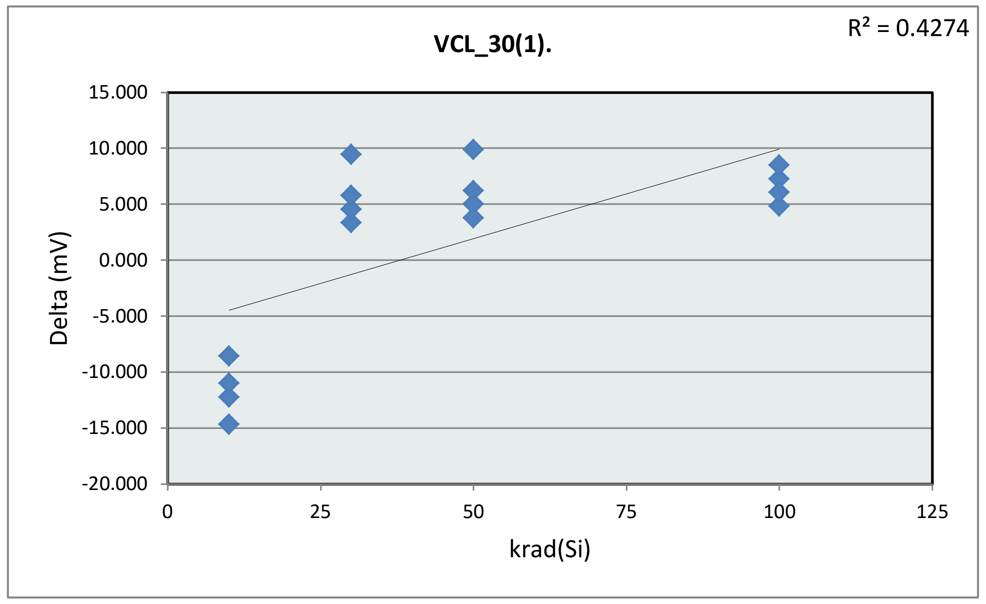
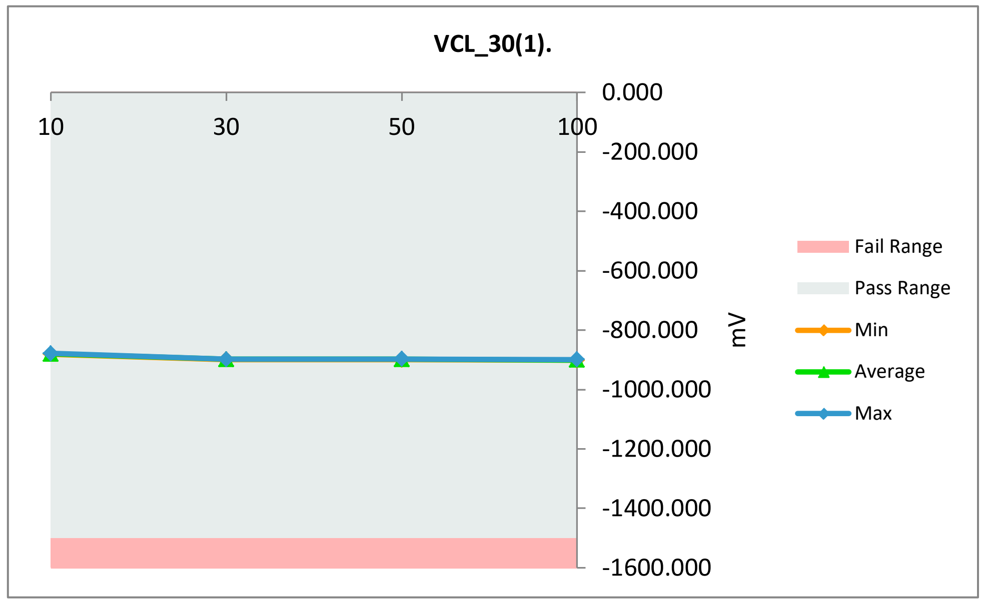
	VCL_30(1).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-1500	-1500

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-894.600	-879.925	-14.675
10	7	-893.379	-878.697	-14.682
10	8	-893.379	-881.153	-12.226
10	9	-892.158	-881.153	-11.005
10	10	-888.495	-879.925	-8.570
30	6	-894.600	-897.937	3.337
30	7	-893.379	-897.937	4.558
30	8	-893.379	-899.158	5.779
30	9	-892.158	-897.937	5.779
30	10	-888.495	-897.937	9.442
50	6	-894.600	-898.386	3.786
50	7	-893.379	-898.386	5.007
50	8	-893.379	-899.607	6.228
50	9	-892.158	-897.164	5.006
50	10	-888.495	-898.386	9.891
100	B011	-893.379	-900.650	7.271
100	B012	-893.379	-901.870	8.491
100	B013	-894.600	-900.650	6.050
100	B014	-894.600	-899.430	4.830
100	B015	-894.600	-900.650	6.050
	Max	-888.495	-878.697	9.891
	Average	-892.830	-894.347	1.517
	Min	-894.600	-901.870	-14.682
	Std Dev	2.038	8.491	8.396

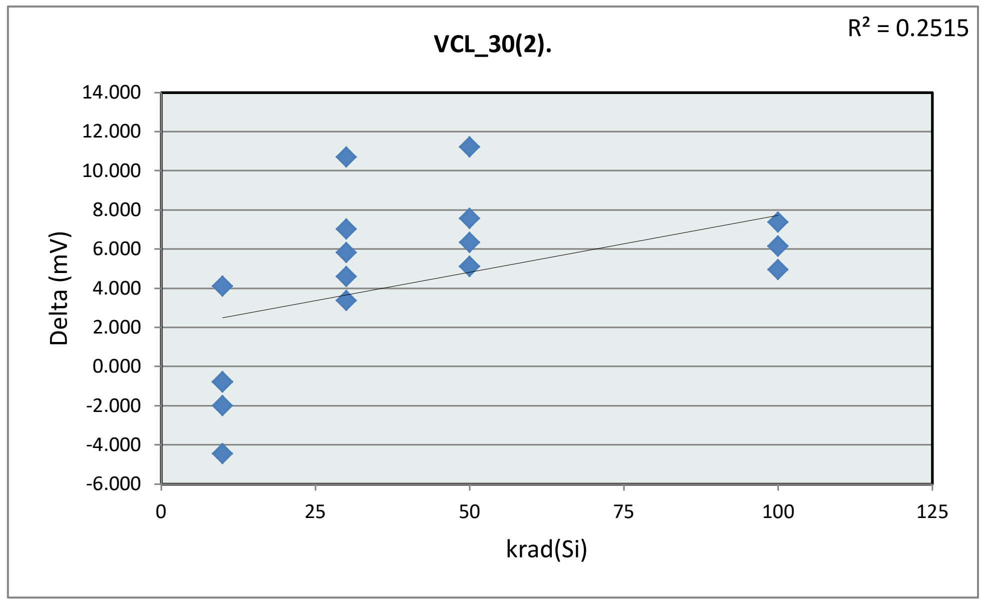


	VCL_30(1).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-1500 mV			
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-881.153	-899.158	-899.607	-901.870
Average	-880.171	-898.181	-898.386	-900.650
Max	-878.697	-897.937	-897.164	-899.430
UL				

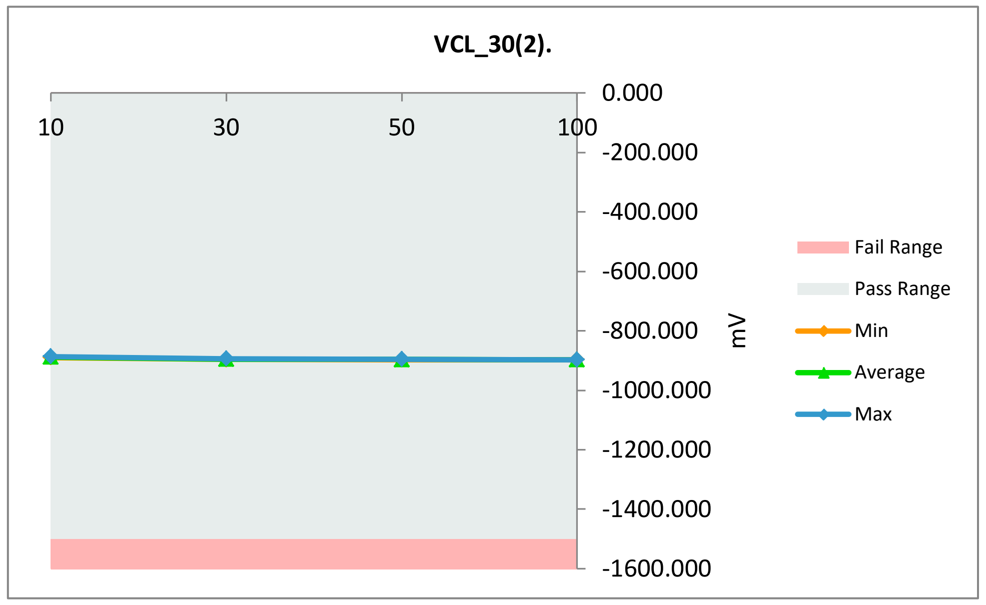


LDR UnBiased TID Report
SN55LVCP22A-SP

		VCL_30(2).		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-1500	-1500	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-890.693	-888.681	-2.012
10	7	-890.693	-886.228	-4.465
10	8	-890.693	-889.907	-0.786
10	9	-888.252	-887.454	-0.798
10	10	-884.591	-888.681	4.090
30	6	-890.693	-895.275	4.582
30	7	-890.693	-894.054	3.361
30	8	-890.693	-896.496	5.803
30	9	-888.252	-895.275	7.023
30	10	-884.591	-895.275	10.684
50	6	-890.693	-895.810	5.117
50	7	-890.693	-895.810	5.117
50	8	-890.693	-897.031	6.338
50	9	-888.252	-895.810	7.558
50	10	-884.591	-895.810	11.219
100	B011	-890.693	-896.846	6.153
100	B012	-889.473	-896.846	7.373
100	B013	-891.914	-896.846	4.932
100	B014	-890.693	-896.846	6.153
100	B015	-890.693	-896.846	6.153
	Max	-884.591	-886.228	11.219
	Average	-889.412	-894.091	4.680
	Min	-891.914	-897.031	-4.465
	Std Dev	2.291	3.630	3.981



	VCL_30(2).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-1500 mV			
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-889.907	-896.496	-897.031	-896.846
Average	-888.190	-895.275	-896.054	-896.846
Max	-886.228	-894.054	-895.810	-896.846
UL				



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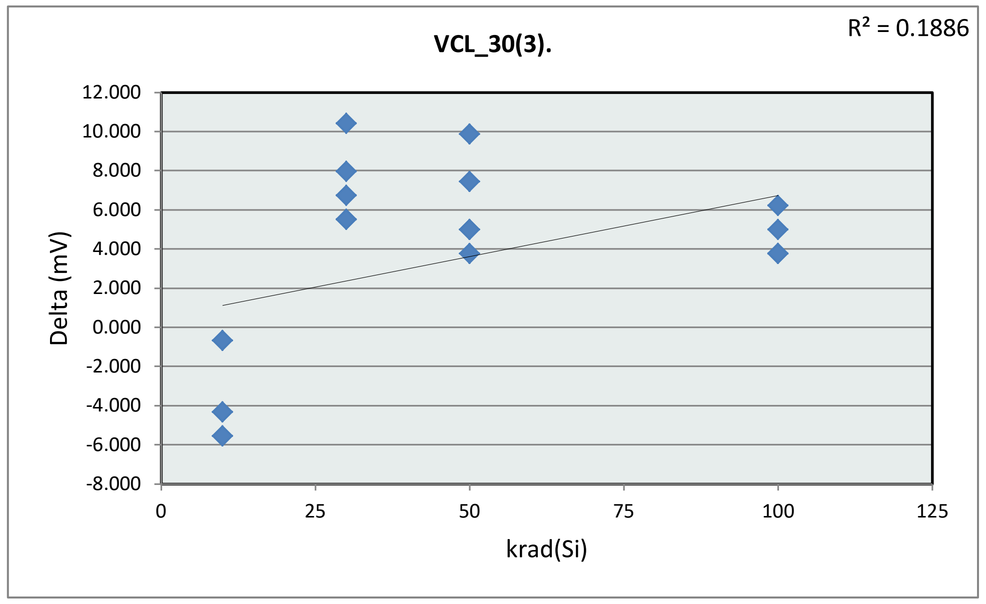
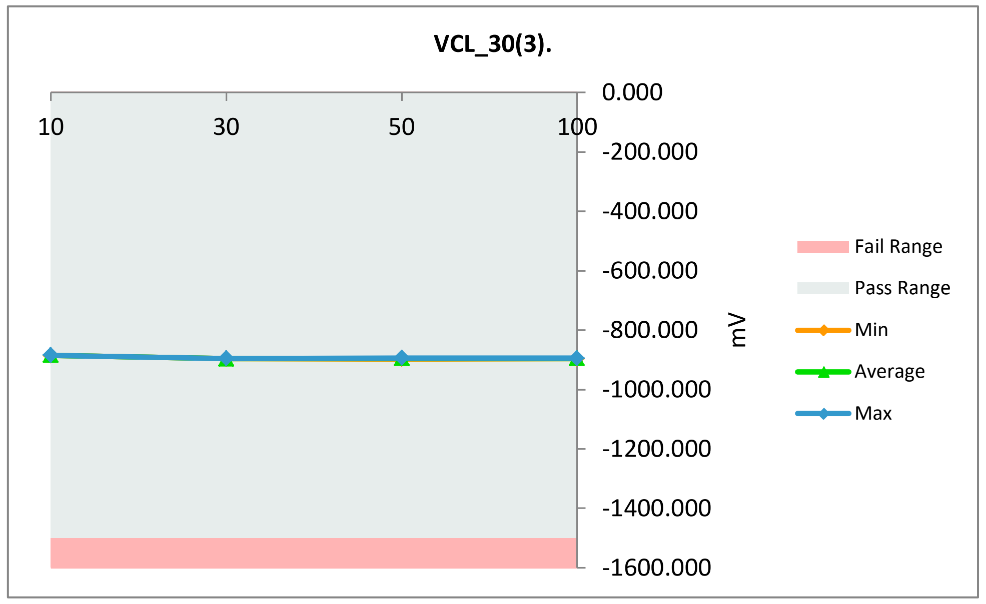
		VCL_30(3).		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-1500	-1500	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-891.239	-885.693	-5.546
10	7	-890.018	-884.464	-5.554
10	8	-890.018	-885.693	-4.325
10	9	-888.797	-884.464	-4.333
10	10	-885.135	-884.464	-0.671
30	6	-891.239	-896.756	5.517
30	7	-890.018	-895.535	5.517
30	8	-890.018	-896.756	6.738
30	9	-888.797	-896.756	7.959
30	10	-885.135	-895.535	10.400
50	6	-891.239	-895.009	3.770
50	7	-890.018	-895.009	4.991
50	8	-890.018	-897.450	7.432
50	9	-888.797	-893.788	4.991
50	10	-885.135	-895.009	9.874
100	B011	-891.239	-896.231	4.992
100	B012	-890.018	-896.231	6.213
100	B013	-892.459	-896.231	3.772
100	B014	-891.239	-895.011	3.772
100	B015	-891.239	-895.011	3.772
	Max	-885.135	-884.464	10.400
	Average	-889.591	-893.055	3.464
	Min	-892.459	-897.450	-5.554
	Std Dev	2.143	4.880	4.922



	VCL_30(3).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-1500 mV			
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-885.693	-896.756	-897.450	-896.231
Average	-884.956	-896.268	-895.253	-895.743
Max	-884.464	-895.535	-893.788	-895.011
UL				



LDR UnBiased TID Report
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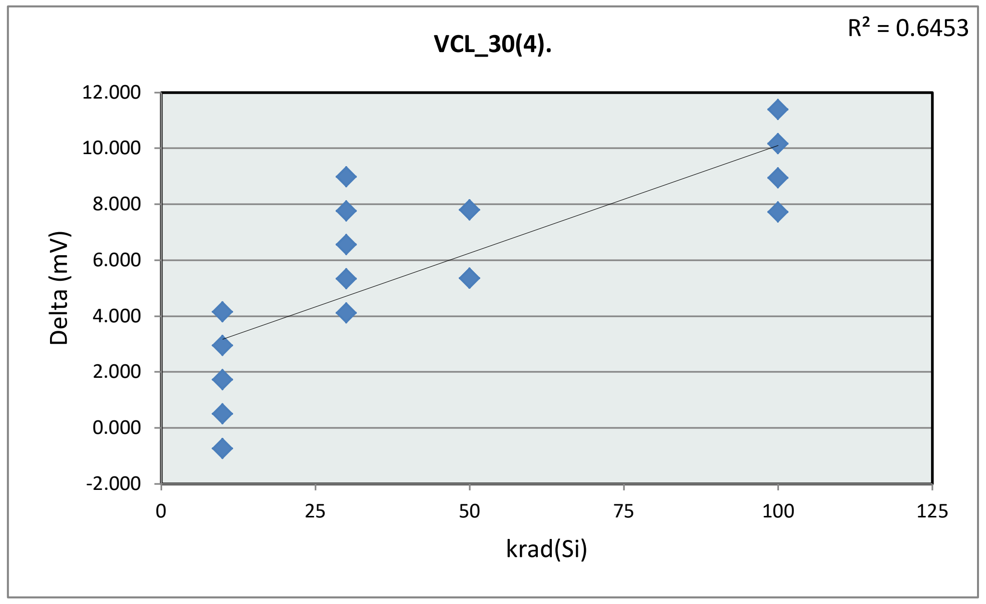
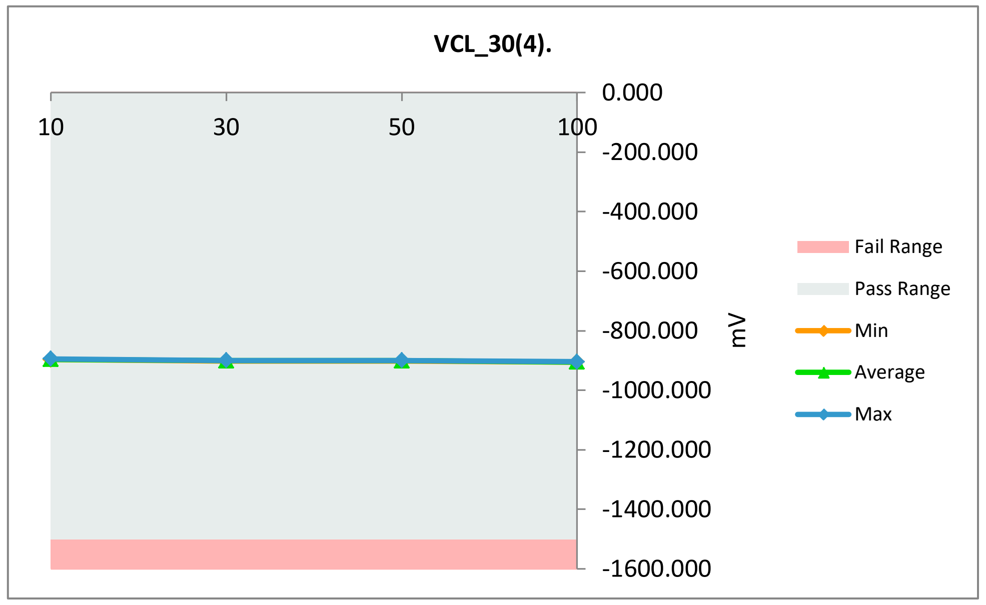
	VCL_30(4).	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-1500	-1500

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-895.446	-895.939	0.493
10	7	-895.446	-894.710	-0.736
10	8	-894.226	-897.167	2.941
10	9	-894.226	-895.939	1.713
10	10	-891.786	-895.939	4.153
30	6	-895.446	-900.766	5.320
30	7	-895.446	-899.546	4.100
30	8	-894.226	-901.987	7.761
30	9	-894.226	-900.766	6.540
30	10	-891.786	-900.766	8.980
50	6	-895.446	-900.792	5.346
50	7	-895.446	-900.792	5.346
50	8	-894.226	-902.012	7.786
50	9	-894.226	-899.572	5.346
50	10	-891.786	-899.572	7.786
100	B011	-895.446	-905.605	10.159
100	B012	-894.226	-905.605	11.379
100	B013	-896.666	-904.385	7.719
100	B014	-895.446	-904.385	8.939
100	B015	-895.446	-905.605	10.159
	Max	-891.786	-894.710	11.379
	Average	-894.531	-900.593	6.062
	Min	-896.666	-905.605	-0.736
	Std Dev	1.364	3.424	3.292



	VCL_30(4).			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-1500 mV			
krad(Si)	10	30	50	100
LL	-1500.000	-1500.000	-1500.000	-1500.000
Min	-897.167	-901.987	-902.012	-905.605
Average	-895.939	-900.766	-900.548	-905.117
Max	-894.710	-899.546	-899.572	-904.385
UL				



LDR UnBiased TID Report
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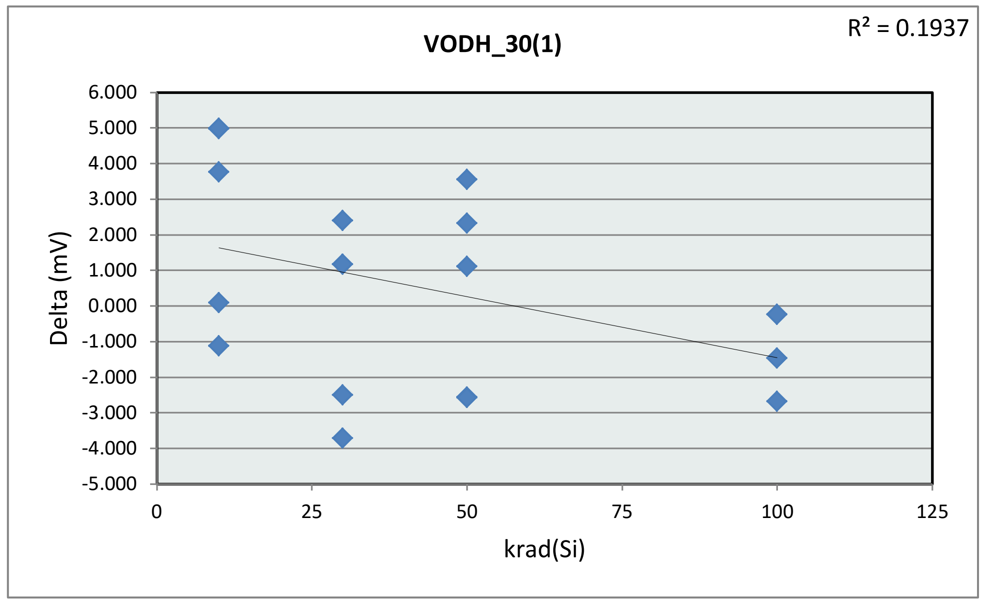
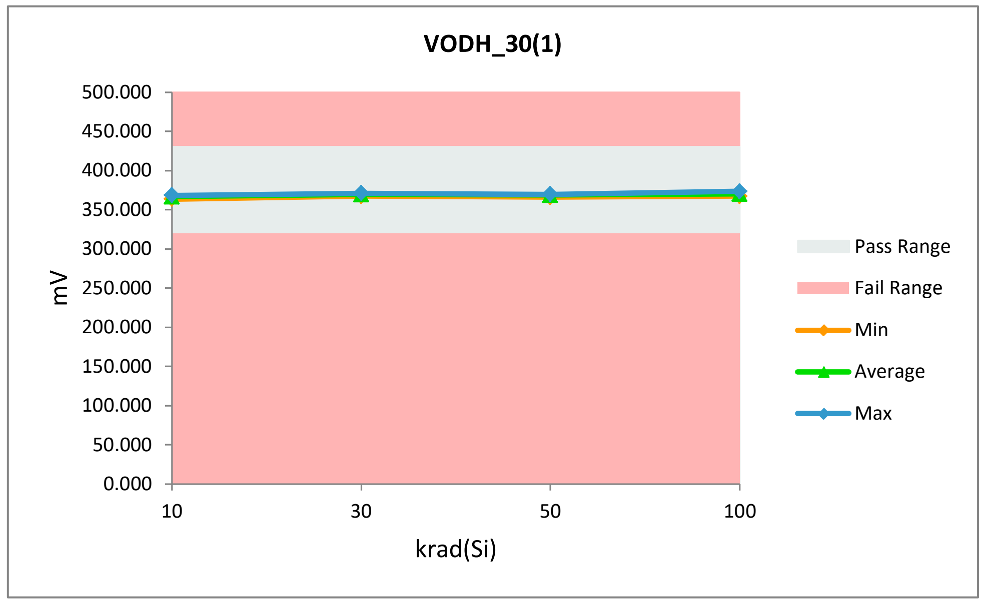
		VODH_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	373.258	368.284	4.974
10	7	365.928	367.056	-1.128
10	8	370.817	367.057	3.760
10	9	368.363	363.375	4.988
10	10	367.141	367.057	0.084
30	6	373.258	370.863	2.395
30	7	365.928	369.641	-3.713
30	8	370.817	369.645	1.172
30	9	368.363	367.196	1.167
30	10	367.141	369.646	-2.505
50	6	373.258	369.709	3.549
50	7	365.928	368.488	-2.560
50	8	370.817	369.715	1.102
50	9	368.363	366.042	2.321
50	10	367.141	369.715	-2.574
100	B011	364.699	367.386	-2.687
100	B012	368.362	369.829	-1.467
100	B013	367.142	367.386	-0.244
100	B014	370.810	372.275	-1.465
100	B015	373.258	373.500	-0.242
	Max	373.258	373.500	4.988
	Average	369.040	368.693	0.346
	Min	364.699	363.375	-3.713
	Std Dev	2.790	2.259	2.667

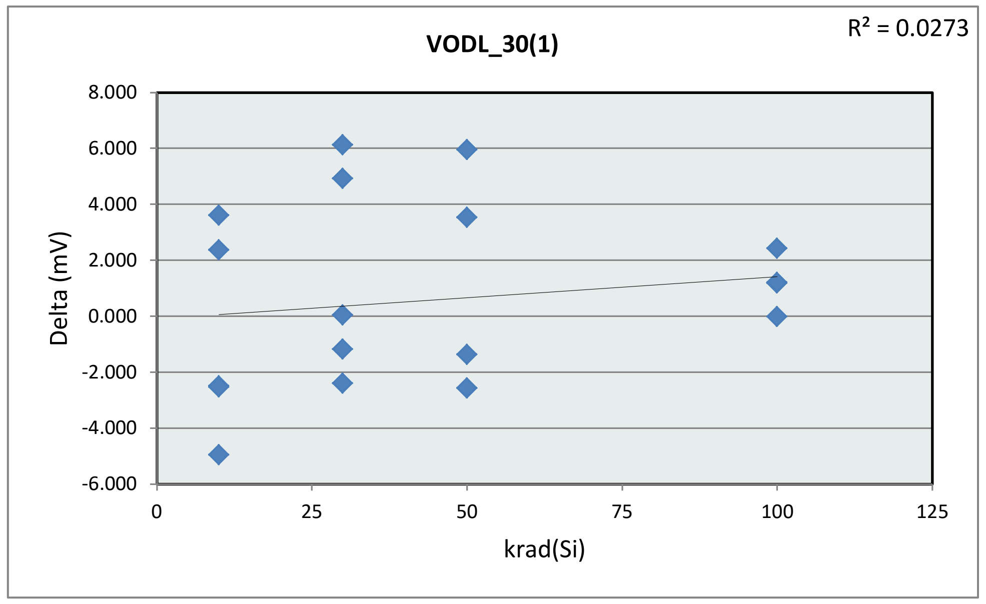


	VODH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	363.375	367.196	366.042	367.386
Average	366.566	369.398	368.734	370.075
Max	368.284	370.863	369.715	373.500
UL	430.000	430.000	430.000	430.000

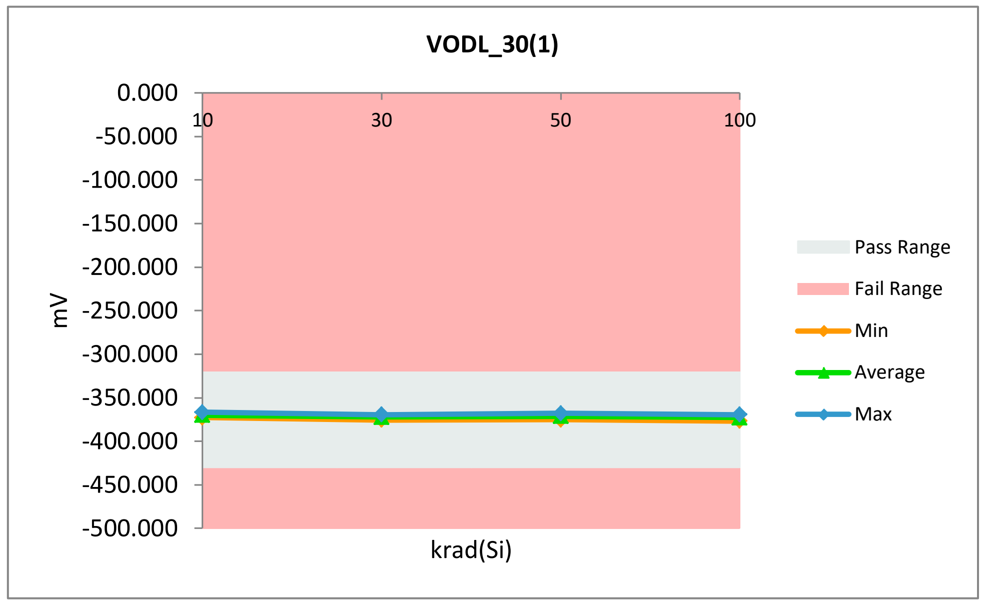


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-375.422	-372.927	-2.495
10	7	-366.874	-369.245	2.371
10	8	-372.978	-368.018	-4.960
10	9	-369.326	-366.791	-2.535
10	10	-369.326	-372.927	3.601
30	6	-375.422	-374.240	-1.182
30	7	-366.874	-371.797	4.923
30	8	-372.978	-370.572	-2.406
30	9	-369.326	-369.357	0.031
30	10	-369.326	-375.457	6.131
50	6	-375.422	-372.845	-2.577
50	7	-366.874	-370.404	3.530
50	8	-372.978	-370.398	-2.580
50	9	-369.326	-367.964	-1.362
50	10	-369.326	-375.282	5.956
100	B011	-368.104	-369.297	1.193
100	B012	-369.327	-370.520	1.193
100	B013	-372.988	-372.962	-0.026
100	B014	-371.763	-374.181	2.418
100	B015	-375.422	-376.622	1.200
	Max	-366.874	-366.791	6.131
	Average	-370.969	-371.590	0.621
	Min	-375.422	-376.622	-4.960
	Std Dev	3.022	2.757	3.165

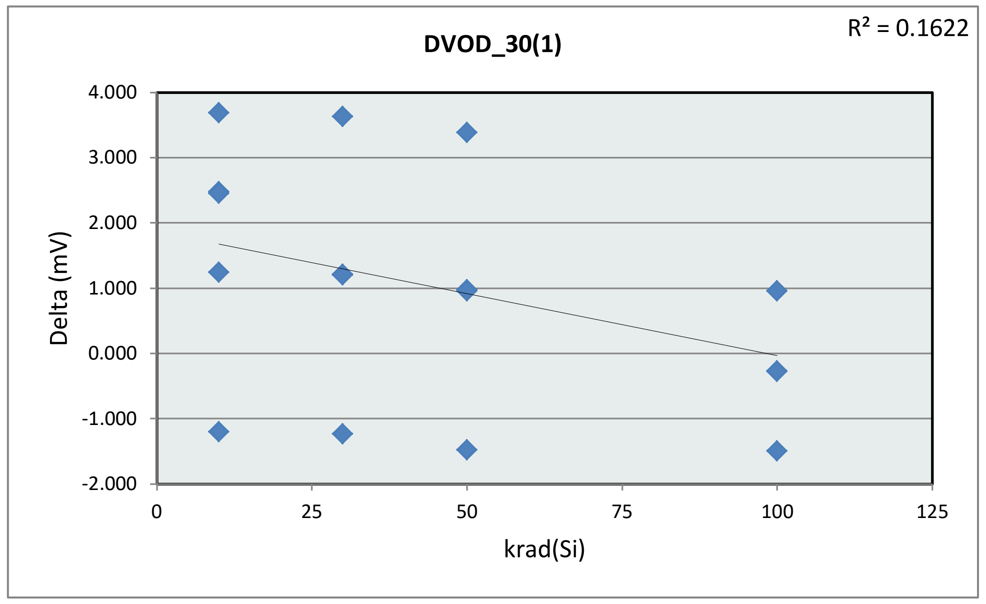


	VODL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-372.927	-375.457	-375.282	-376.622
Average	-369.982	-372.285	-371.379	-372.716
Max	-366.791	-369.357	-367.964	-369.297
UL	-320.000	-320.000	-320.000	-320.000

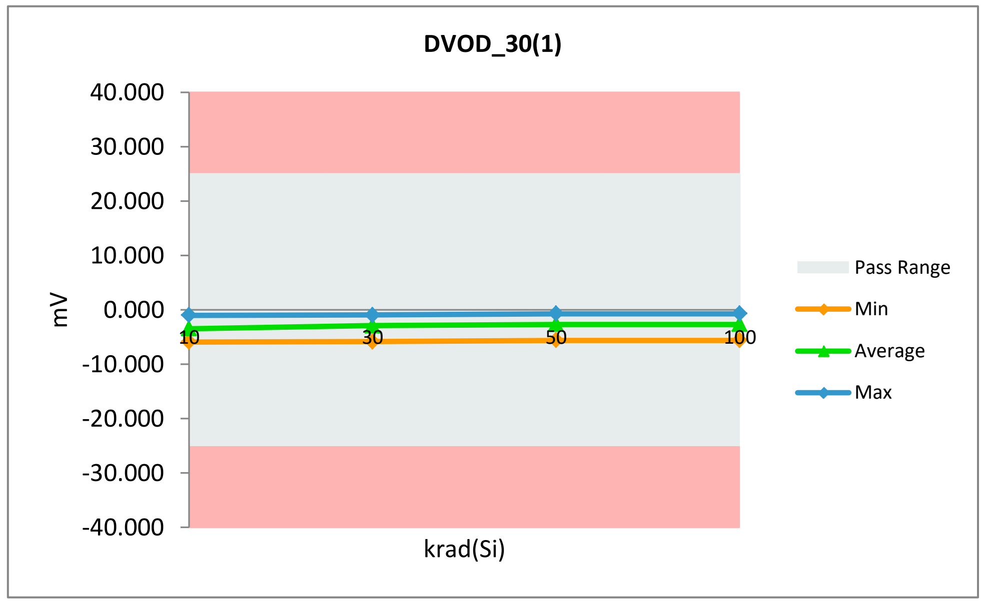


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-2.165	-4.643	2.478
10	7	-0.946	-2.189	1.242
10	8	-2.161	-0.961	-1.200
10	9	-0.963	-3.416	2.453
10	10	-2.185	-5.870	3.685
30	6	-2.165	-3.377	1.212
30	7	-0.946	-2.156	1.210
30	8	-2.161	-0.927	-1.234
30	9	-0.963	-2.161	1.198
30	10	-2.185	-5.812	3.627
50	6	-2.165	-3.137	0.972
50	7	-0.946	-1.916	0.970
50	8	-2.161	-0.683	-1.478
50	9	-0.963	-1.922	0.959
50	10	-2.185	-5.568	3.383
100	B011	-3.405	-1.911	-1.494
100	B012	-0.965	-0.691	-0.274
100	B013	-5.846	-5.576	-0.270
100	B014	-0.953	-1.907	0.954
100	B015	-2.165	-3.122	0.957
	Max	-0.946	-0.683	3.685
	Average	-1.930	-2.897	0.968
	Min	-5.846	-5.870	-1.494
	Std Dev	1.163	1.750	1.617

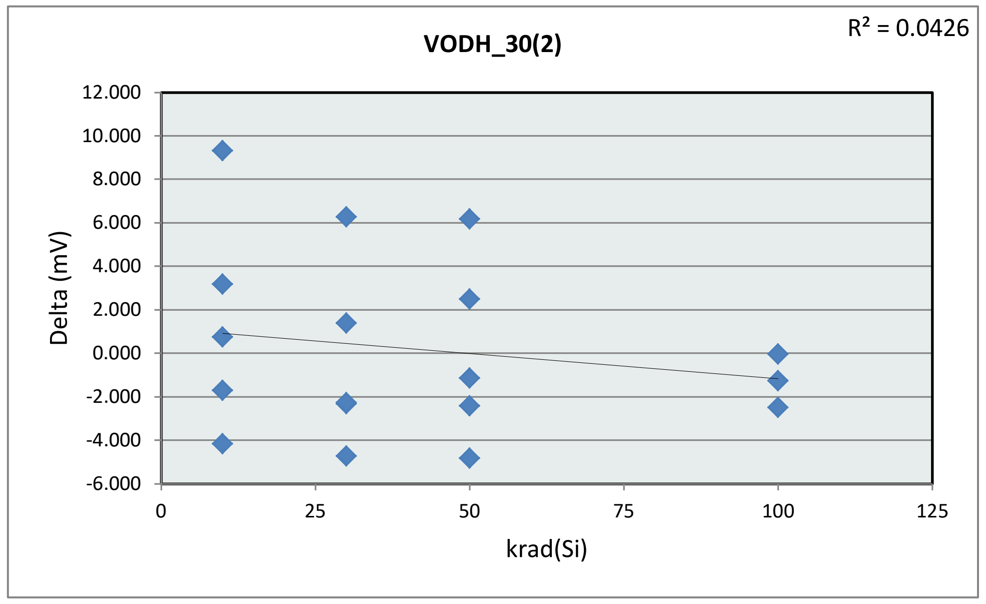


	DVOD_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-5.870	-5.812	-5.568	-5.576
Average	-3.416	-2.887	-2.645	-2.641
Max	-0.961	-0.927	-0.683	-0.691
UL	25.000	25.000	25.000	25.000

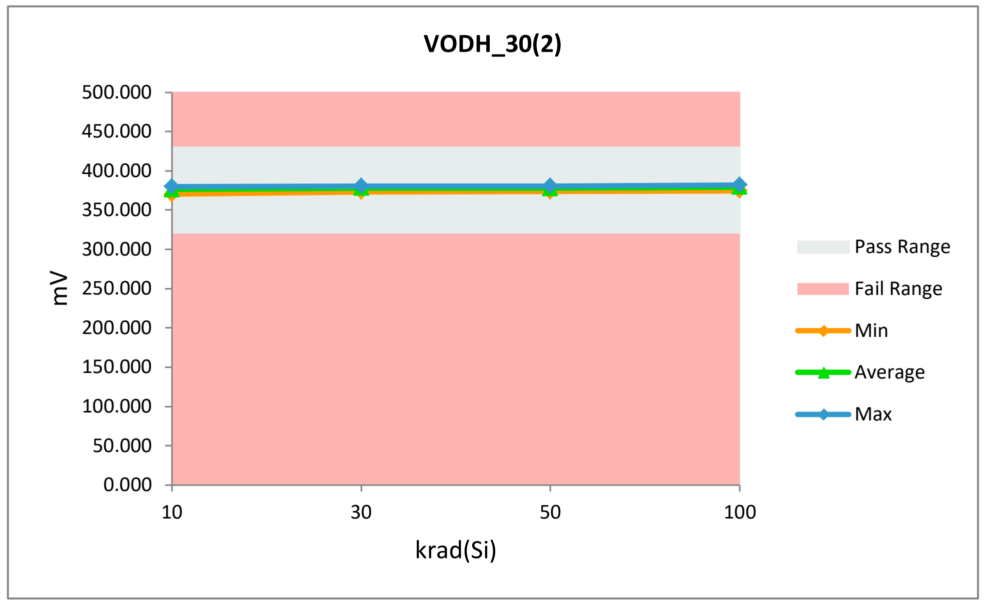


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	381.991	378.818	3.173
10	7	374.646	376.366	-1.720
10	8	379.541	370.224	9.317
10	9	375.888	375.135	0.753
10	10	375.887	380.045	-4.158
30	6	381.991	380.614	1.377
30	7	374.646	376.960	-2.314
30	8	379.541	373.263	6.278
30	9	375.888	378.164	-2.276
30	10	375.887	380.614	-4.727
50	6	381.991	379.491	2.500
50	7	374.646	377.058	-2.412
50	8	379.541	373.368	6.173
50	9	375.888	377.045	-1.157
50	10	375.887	380.714	-4.827
100	B011	379.532	380.792	-1.260
100	B012	377.102	379.587	-2.485
100	B013	373.415	374.675	-1.260
100	B014	379.531	379.567	-0.036
100	B015	381.991	382.031	-0.040
	Max	381.991	382.031	9.317
	Average	377.771	377.727	0.045
	Min	373.415	370.224	-4.827
	Std Dev	2.873	3.119	3.811



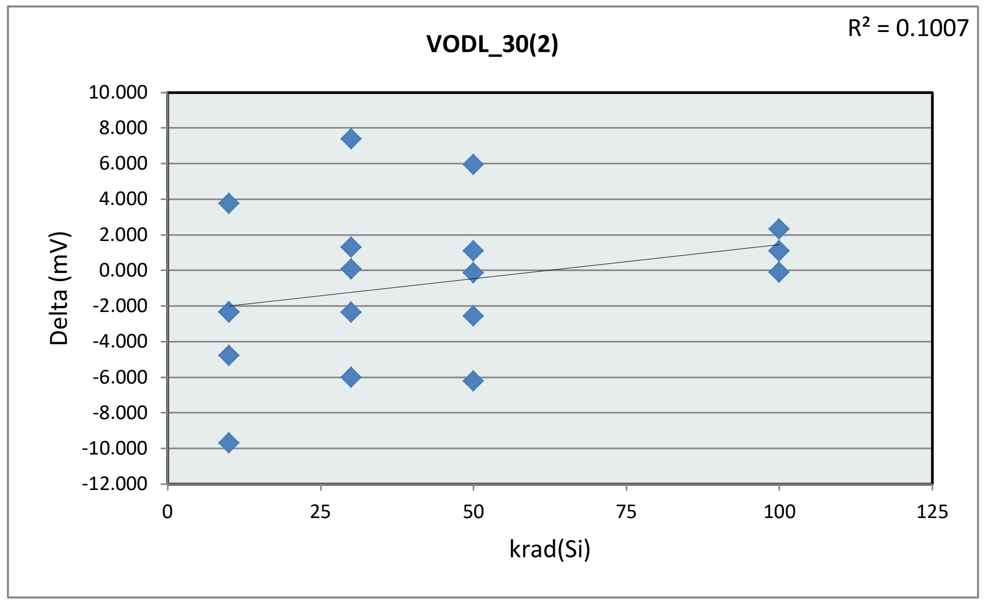
	VODH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	370.224	373.263	373.368	374.675
Average	376.118	377.923	377.535	379.330
Max	380.045	380.614	380.714	382.031
UL	430.000	430.000	430.000	430.000



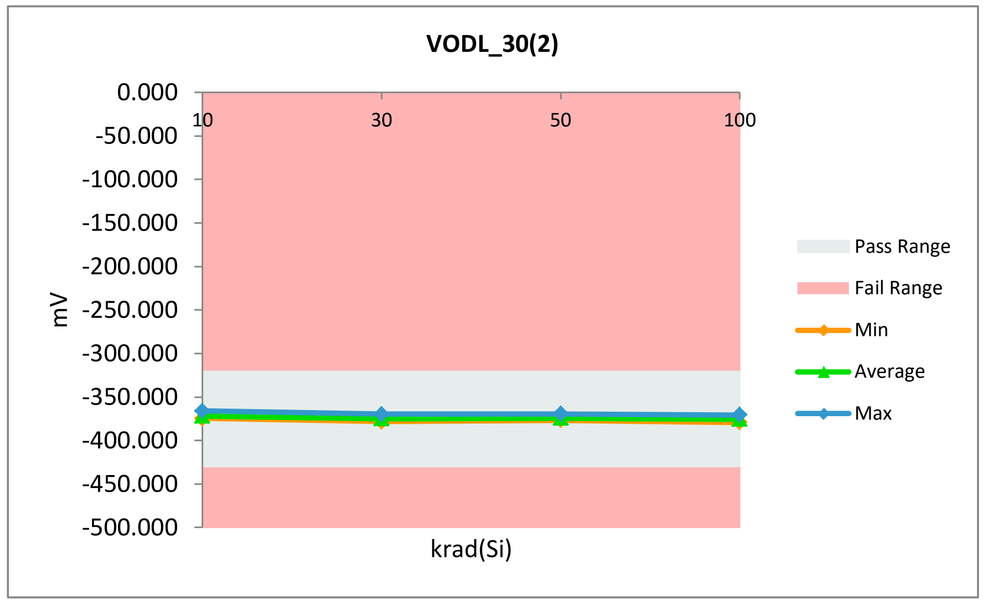
LDR UnBiased TID Report
SN55LVCP22A-SP

	VODL_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-375.779	-373.435	-2.344
10	7	-370.901	-374.659	3.758
10	8	-375.784	-366.076	-9.708
10	9	-375.769	-370.982	-4.787
10	10	-375.771	-373.435	-2.336
30	6	-375.779	-375.846	0.067
30	7	-370.901	-378.277	7.376
30	8	-375.784	-369.755	-6.029
30	9	-375.769	-373.407	-2.362
30	10	-375.771	-377.069	1.298
50	6	-375.779	-375.645	-0.134
50	7	-370.901	-376.856	5.955
50	8	-375.784	-369.549	-6.235
50	9	-375.769	-373.204	-2.565
50	10	-375.771	-376.866	1.095
100	B011	-377.014	-379.335	2.321
100	B012	-374.557	-375.651	1.094
100	B013	-369.688	-370.787	1.099
100	B014	-374.571	-374.448	-0.123
100	B015	-375.779	-376.874	1.095
	Max	-369.688	-366.076	7.376
	Average	-374.681	-374.108	-0.573
	Min	-377.014	-379.335	-9.708
	Std Dev	2.163	3.338	4.135

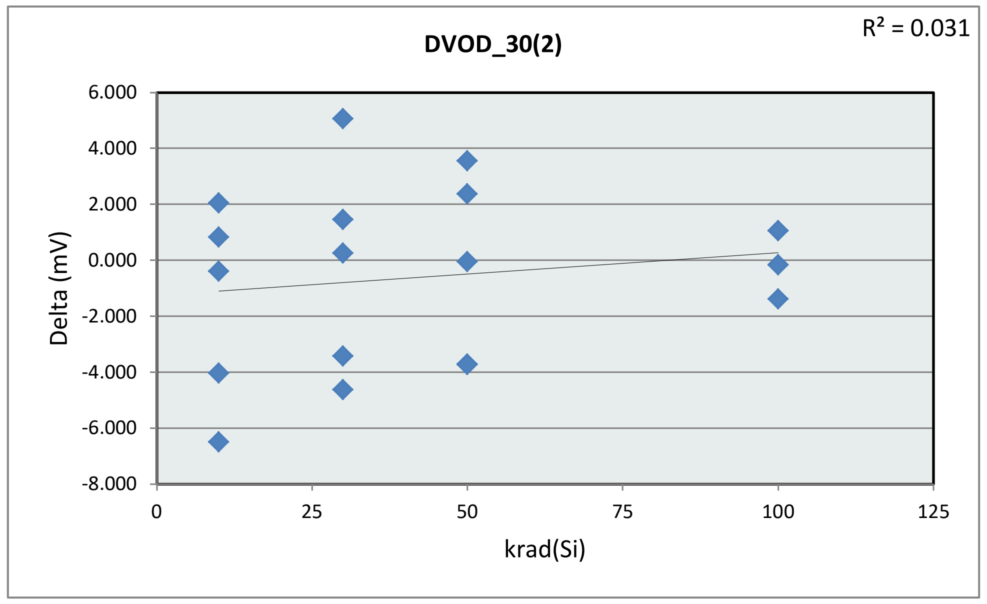


	VODL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-374.659	-378.277	-376.866	-379.335
Average	-371.717	-374.871	-374.424	-375.419
Max	-366.076	-369.755	-369.549	-370.787
UL	-320.000	-320.000	-320.000	-320.000

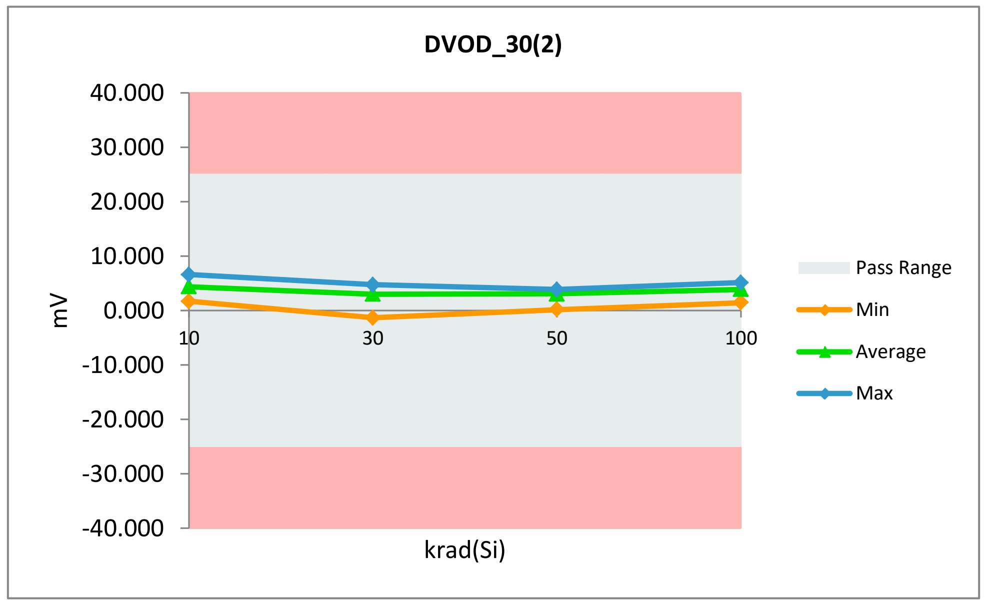


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	6.212	5.384	0.828
10	7	3.745	1.707	2.038
10	8	3.758	4.148	-0.390
10	9	0.119	4.153	-4.034
10	10	0.116	6.610	-6.494
30	6	6.212	4.768	1.444
30	7	3.745	-1.317	5.062
30	8	3.758	3.509	0.249
30	9	0.119	4.757	-4.638
30	10	0.116	3.545	-3.429
50	6	6.212	3.846	2.366
50	7	3.745	0.202	3.543
50	8	3.758	3.819	-0.061
50	9	0.119	3.841	-3.722
50	10	0.116	3.848	-3.732
100	B011	2.518	1.457	1.061
100	B012	2.545	3.935	-1.390
100	B013	3.728	3.888	-0.160
100	B014	4.960	5.120	-0.160
100	B015	6.212	5.156	1.056
	Max	6.212	6.610	5.062
	Average	3.091	3.619	-0.528
	Min	0.116	-1.317	-6.494
	Std Dev	2.284	1.844	2.983

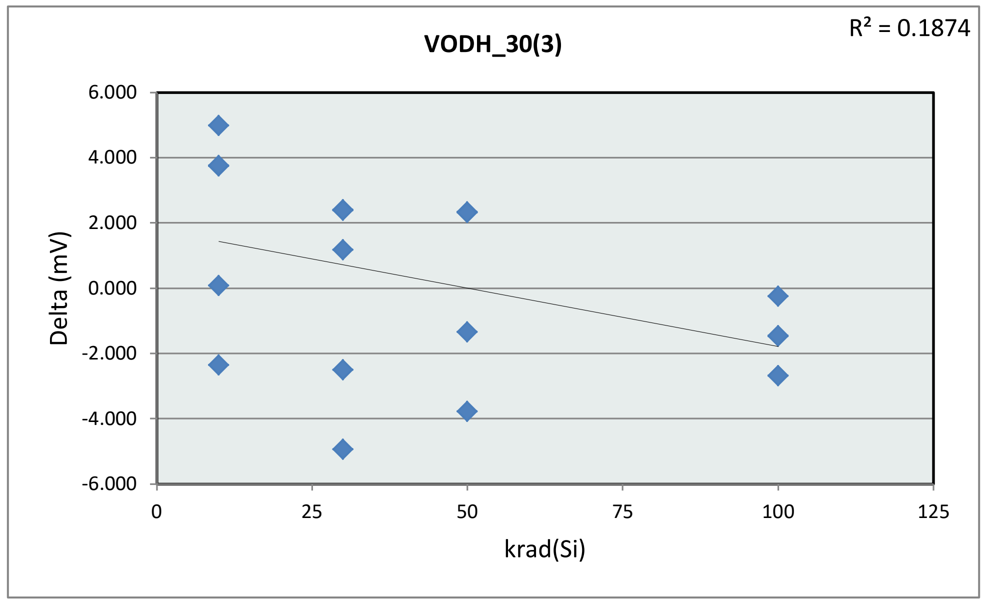


	DVOD_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	1.707	-1.317	0.202	1.457
Average	4.400	3.052	3.111	3.911
Max	6.610	4.768	3.848	5.156
UL	25.000	25.000	25.000	25.000

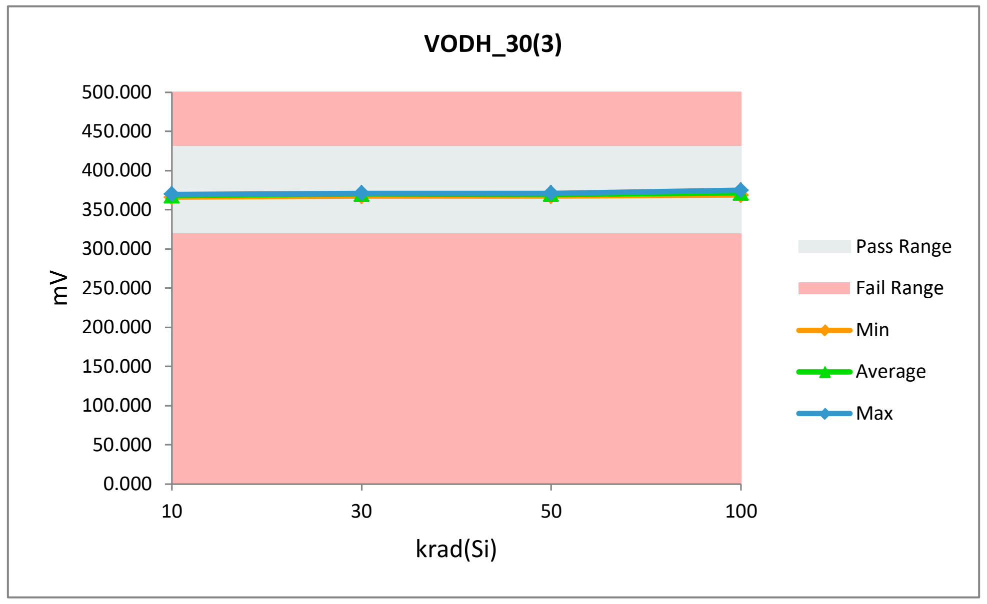


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	373.252	369.511	3.741
10	7	365.923	368.284	-2.361
10	8	372.032	367.057	4.975
10	9	369.578	365.829	3.749
10	10	368.356	368.284	0.072
30	6	373.252	370.858	2.394
30	7	365.923	370.858	-4.935
30	8	372.032	370.863	1.169
30	9	369.578	367.192	2.386
30	10	368.356	370.863	-2.507
50	6	373.252	370.924	2.328
50	7	365.923	369.703	-3.780
50	8	372.032	369.709	2.323
50	9	369.578	367.258	2.320
50	10	368.356	369.710	-1.354
100	B011	365.915	368.604	-2.689
100	B012	368.356	371.047	-2.691
100	B013	368.357	369.826	-1.469
100	B014	372.025	372.272	-0.247
100	B015	373.252	374.718	-1.466
	Max	373.252	374.718	4.975
	Average	369.766	369.668	0.098
	Min	365.915	365.829	-4.935
	Std Dev	2.698	2.051	2.836

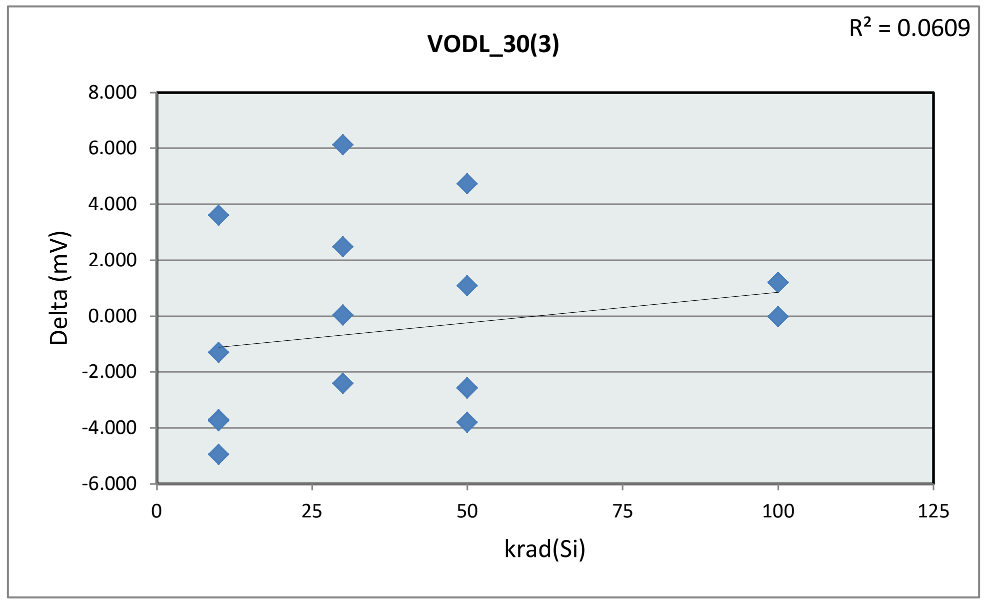


	VODH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	365.829	367.192	367.258	368.604
Average	367.793	370.127	369.461	371.293
Max	369.511	370.863	370.924	374.718
UL	430.000	430.000	430.000	430.000

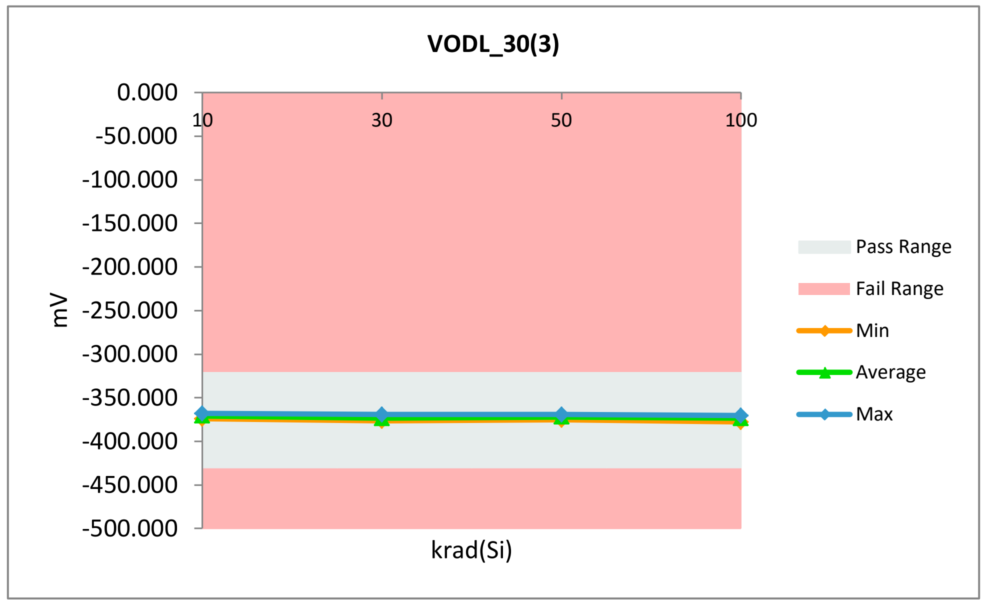


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-376.649	-372.927	-3.722
10	7	-370.544	-369.245	-1.299
10	8	-374.206	-369.245	-4.961
10	9	-371.775	-368.018	-3.757
10	10	-370.554	-374.154	3.600
30	6	-376.649	-376.687	0.038
30	7	-370.544	-373.023	2.479
30	8	-374.206	-371.797	-2.409
30	9	-371.775	-369.361	-2.414
30	10	-370.554	-376.683	6.129
50	6	-376.649	-374.073	-2.576
50	7	-370.544	-371.630	1.086
50	8	-374.206	-370.404	-3.802
50	9	-371.775	-369.191	-2.584
50	10	-370.554	-375.288	4.734
100	B011	-369.331	-370.522	1.191
100	B012	-371.775	-371.745	-0.030
100	B013	-372.995	-374.186	1.191
100	B014	-374.212	-374.185	-0.027
100	B015	-376.649	-377.847	1.198
	Max	-369.331	-368.018	6.129
	Average	-372.807	-372.511	-0.297
	Min	-376.649	-377.847	-4.961
	Std Dev	2.448	2.856	3.047



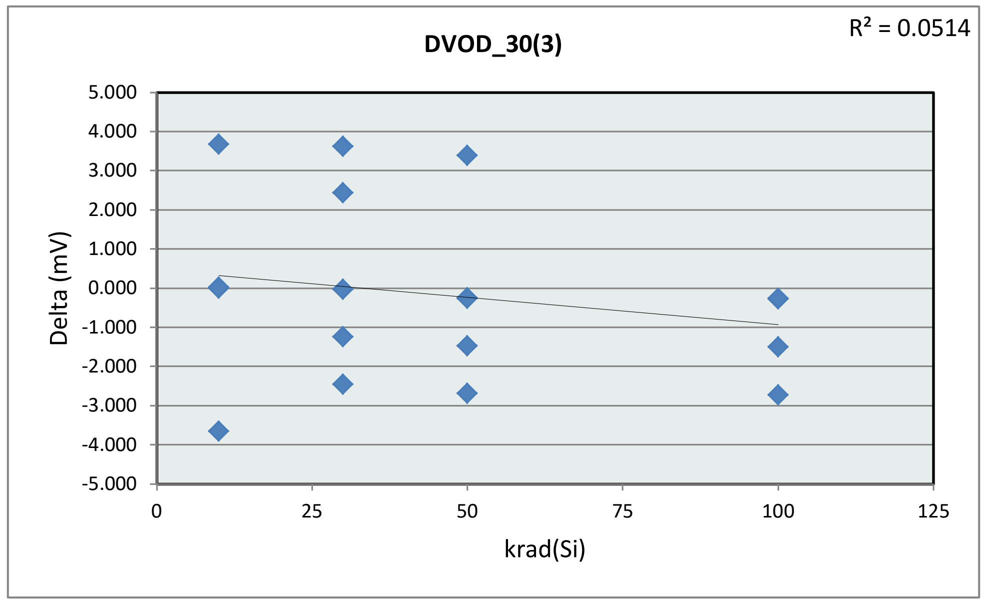
	VODL_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-374.154	-376.687	-375.288	-377.847
Average	-370.718	-373.510	-372.117	-373.697
Max	-368.018	-369.361	-369.191	-370.522
UL	-320.000	-320.000	-320.000	-320.000



LDR UnBiased TID Report
SN55LVCP22A-SP

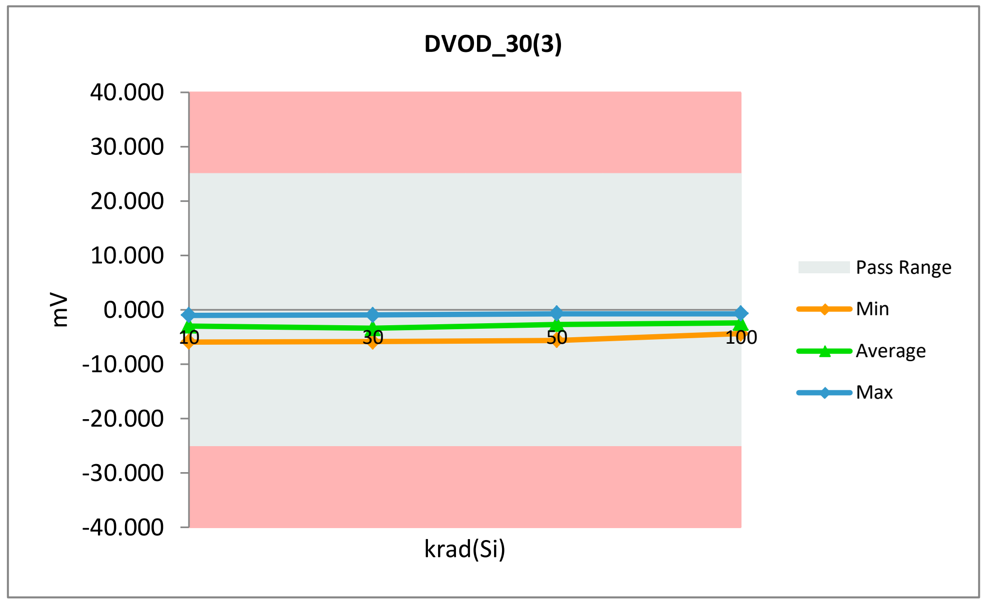
	DVOD_30(3)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-3.398	-3.416	0.018
10	7	-4.621	-0.962	-3.659
10	8	-2.174	-2.189	0.015
10	9	-2.197	-2.189	-0.008
10	10	-2.198	-5.870	3.672
30	6	-3.398	-5.828	2.430
30	7	-4.621	-2.164	-2.457
30	8	-2.174	-0.935	-1.239
30	9	-2.197	-2.169	-0.028
30	10	-2.198	-5.820	3.622
50	6	-3.398	-3.149	-0.249
50	7	-4.621	-1.927	-2.694
50	8	-2.174	-0.695	-1.479
50	9	-2.197	-1.933	-0.264
50	10	-2.198	-5.578	3.380
100	B011	-3.416	-1.918	-1.498
100	B012	-3.420	-0.698	-2.722
100	B013	-4.638	-4.360	-0.278
100	B014	-2.187	-1.913	-0.274
100	B015	-3.398	-3.129	-0.269
	Max	-2.174	-0.695	3.672
	Average	-3.041	-2.842	-0.199
	Min	-4.638	-5.870	-3.659
	Std Dev	0.976	1.759	2.097



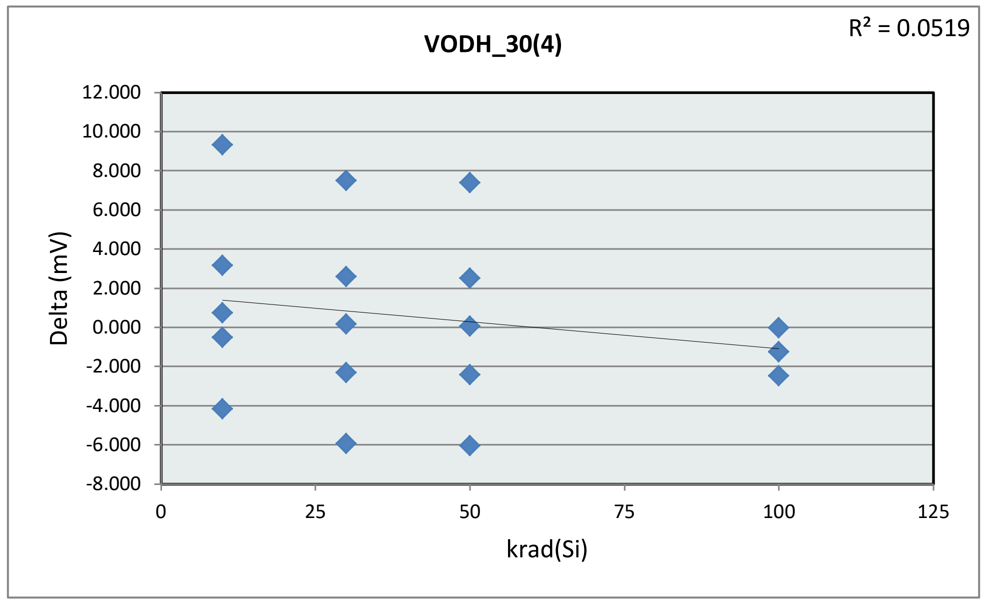
	DVOD_30(3)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-5.870	-5.828	-5.578	-4.360
Average	-2.925	-3.383	-2.656	-2.404
Max	-0.962	-0.935	-0.695	-0.698
UL	25.000	25.000	25.000	25.000

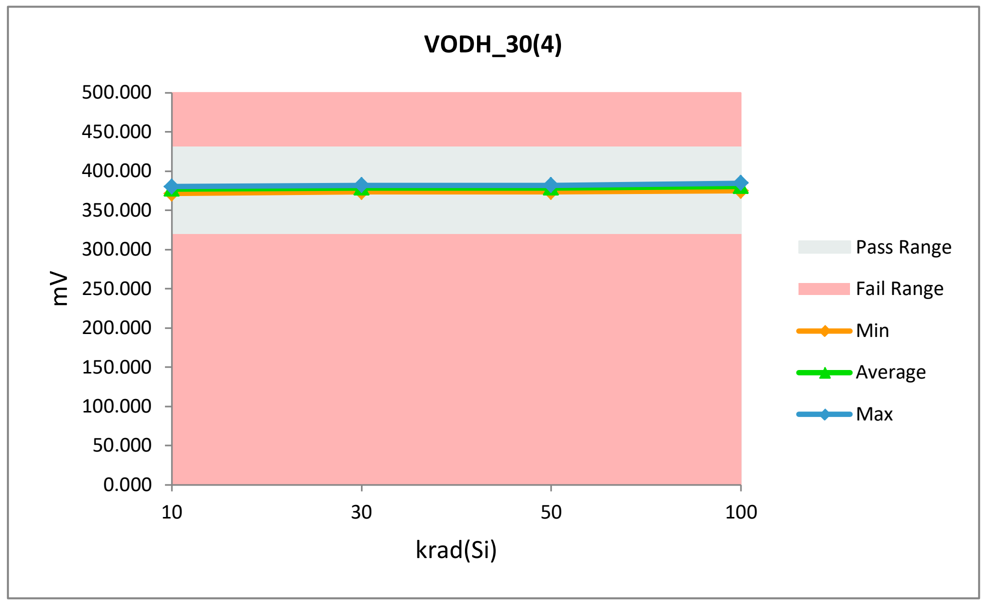


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbias	Delta
10	6	383.206	380.043	3.163
10	7	375.860	376.363	-0.503
10	8	380.755	371.448	9.307
10	9	378.324	377.587	0.737
10	10	375.878	380.043	-4.165
30	6	383.206	380.603	2.603
30	7	375.860	378.170	-2.310
30	8	380.755	373.252	7.503
30	9	378.324	378.153	0.171
30	10	375.878	381.824	-5.946
50	6	383.206	380.704	2.502
50	7	375.860	378.270	-2.410
50	8	380.755	373.359	7.396
50	9	378.324	378.257	0.067
50	10	375.878	381.926	-6.048
100	B011	380.746	382.003	-1.257
100	B012	378.315	380.799	-2.484
100	B013	374.629	374.666	-0.037
100	B014	380.745	380.780	-0.035
100	B015	383.206	384.466	-1.260
	Max	383.206	384.466	9.307
	Average	378.985	378.636	0.350
	Min	374.629	371.448	-6.048
	Std Dev	2.955	3.395	4.160

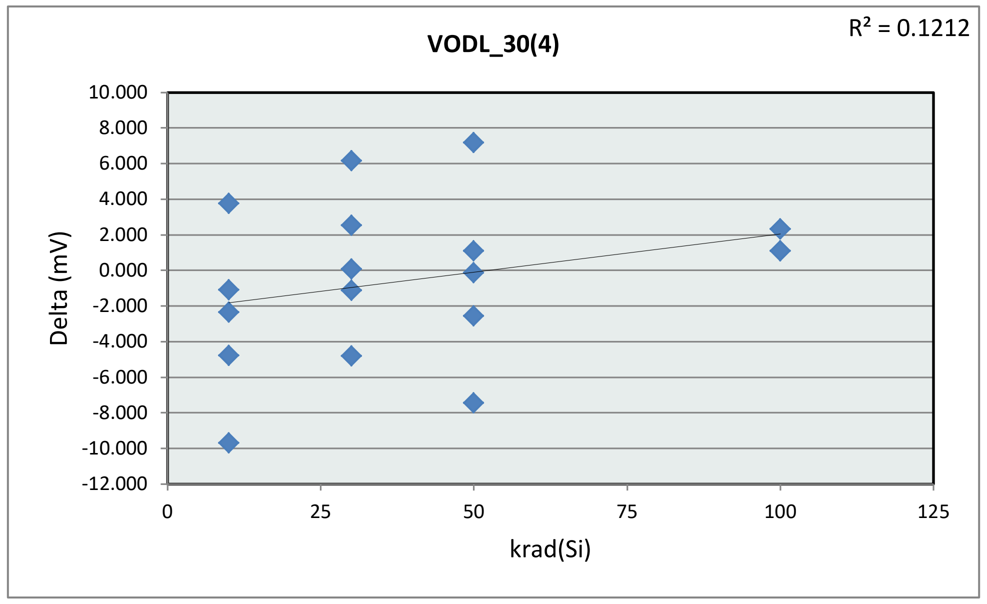


	VODH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	371.448	373.252	373.359	374.666
Average	377.097	378.400	378.503	380.543
Max	380.043	381.824	381.926	384.466
UL	430.000	430.000	430.000	430.000

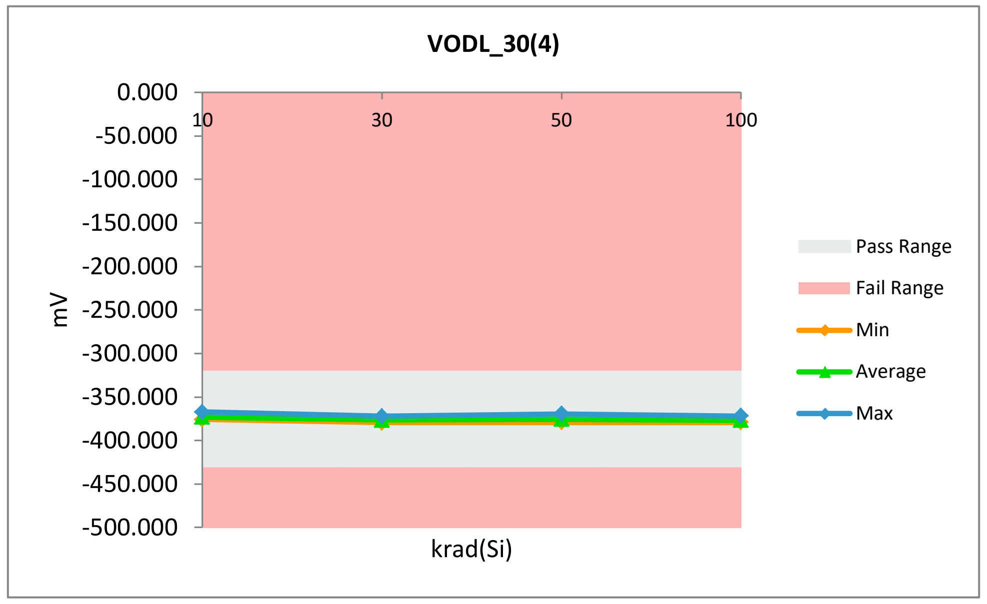


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-377.009	-374.665	-2.344
10	7	-372.132	-375.889	3.757
10	8	-377.014	-367.306	-9.708
10	9	-377.000	-372.211	-4.789
10	10	-377.001	-375.892	-1.109
30	6	-377.009	-377.080	0.071
30	7	-372.132	-378.290	6.158
30	8	-377.014	-372.210	-4.804
30	9	-377.000	-375.862	-1.138
30	10	-377.001	-379.524	2.523
50	6	-377.009	-376.875	-0.134
50	7	-372.132	-379.309	7.177
50	8	-377.014	-369.558	-7.456
50	9	-377.000	-374.436	-2.564
50	10	-377.001	-378.098	1.097
100	B011	-377.024	-379.345	2.321
100	B012	-375.788	-376.883	1.095
100	B013	-370.918	-372.019	1.101
100	B014	-374.581	-376.902	2.321
100	B015	-377.009	-379.327	2.318
	Max	-370.918	-367.306	7.177
	Average	-375.789	-375.584	-0.205
	Min	-377.024	-379.524	-9.708
	Std Dev	2.129	3.413	4.226



	VODL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-375.892	-379.524	-379.309	-379.345
Average	-373.193	-376.593	-375.655	-376.895
Max	-367.306	-372.210	-369.558	-372.019
UL	-320.000	-320.000	-320.000	-320.000



LDR UnBiased TID Report
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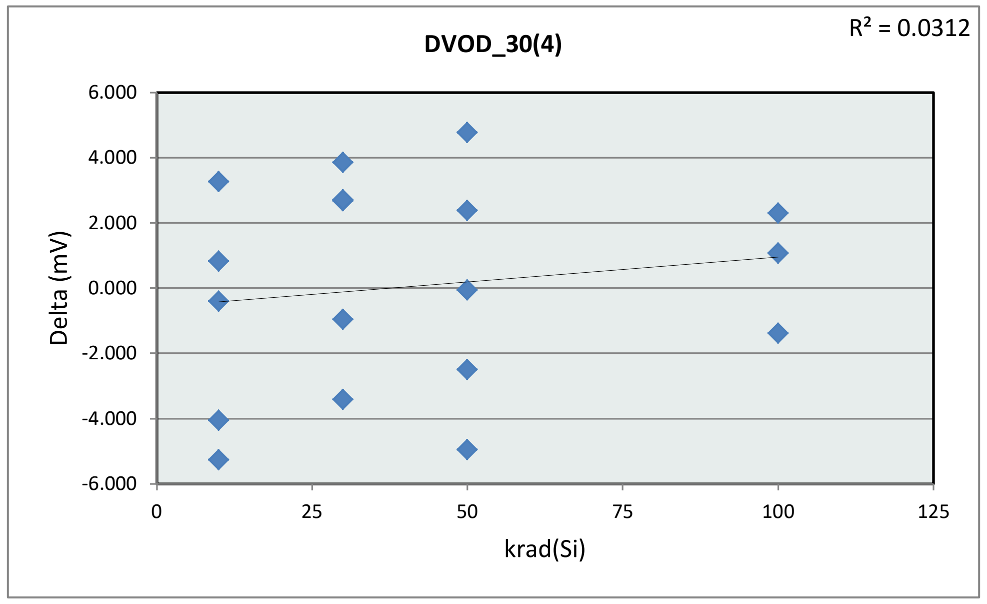
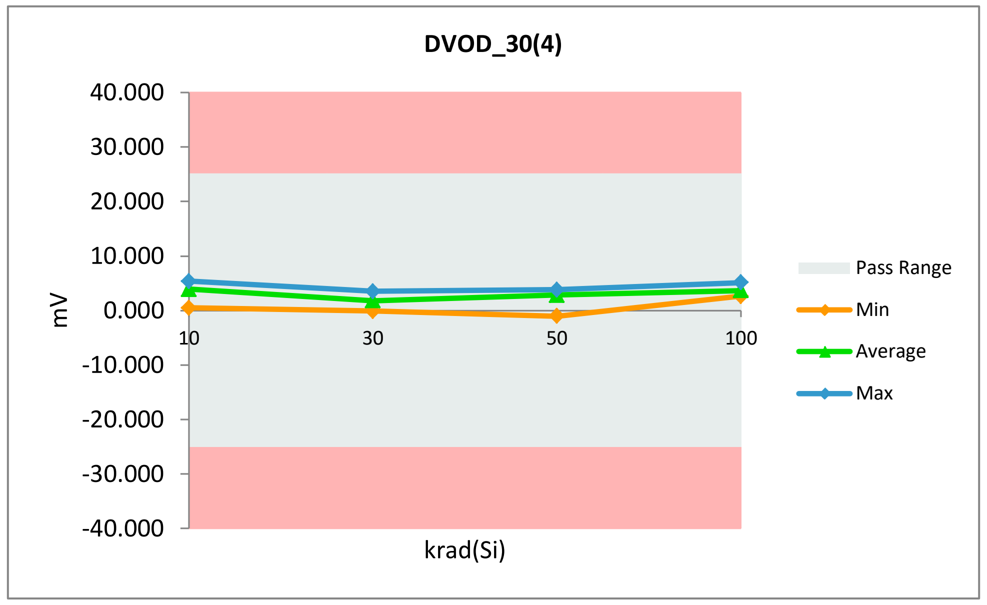
	DVOD_30(4)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	mV	mV	
Max Limit	25	25	
Min Limit	-25	-25	

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	6.197	5.378	0.819
10	7	3.728	0.474	3.254
10	8	3.741	4.143	-0.402
10	9	1.324	5.376	-4.052
10	10	-1.123	4.151	-5.274
30	6	6.197	3.523	2.674
30	7	3.728	-0.120	3.848
30	8	3.741	1.042	2.699
30	9	1.324	2.291	-0.967
30	10	-1.123	2.300	-3.423
50	6	6.197	3.829	2.368
50	7	3.728	-1.038	4.766
50	8	3.741	3.801	-0.060
50	9	1.324	3.821	-2.497
50	10	-1.123	3.829	-4.952
100	B011	3.722	2.658	1.064
100	B012	2.527	3.916	-1.389
100	B013	3.711	2.647	1.064
100	B014	6.164	3.877	2.287
100	B015	6.197	5.139	1.058
	Max	6.197	5.378	4.766
	Average	3.196	3.052	0.144
	Min	-1.123	-1.038	-5.274
	Std Dev	2.450	1.785	2.963



	DVOD_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.474	-0.120	-1.038	2.647
Average	3.904	1.807	2.848	3.647
Max	5.378	3.523	3.829	5.139
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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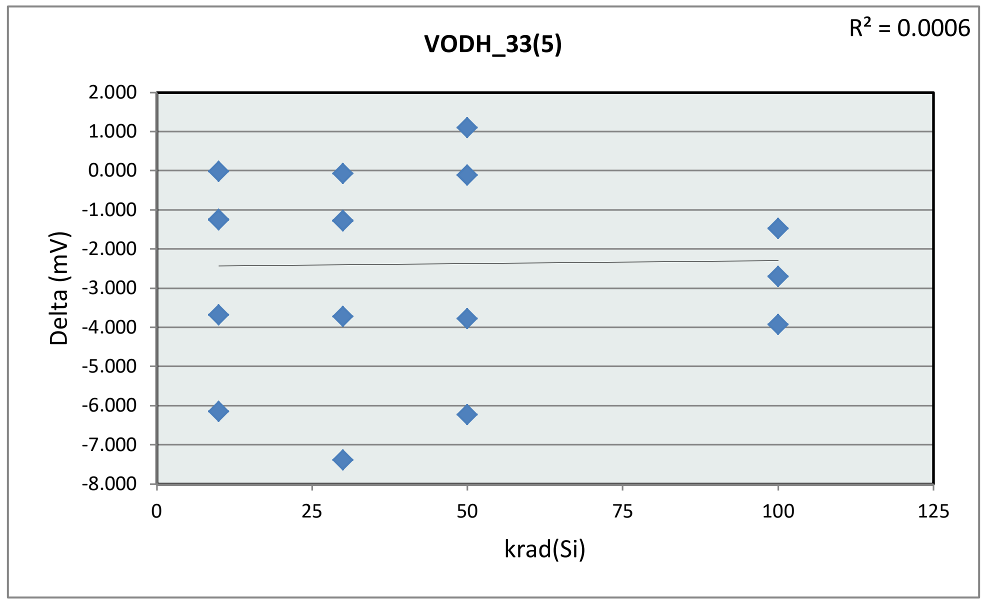
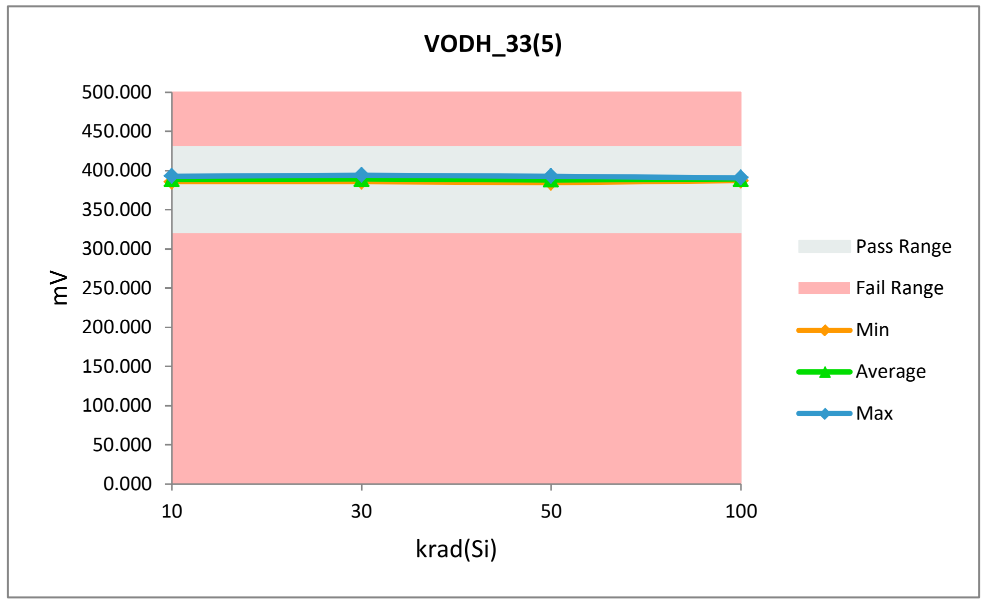
	VODH_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	384.228	387.918	-3.690
10	7	387.893	389.146	-1.253
10	8	386.673	392.827	-6.154
10	9	386.663	387.918	-1.255
10	10	385.441	385.464	-0.023
30	6	384.228	387.949	-3.721
30	7	387.893	389.171	-1.278
30	8	386.673	394.060	-7.387
30	9	386.663	387.948	-1.285
30	10	385.441	385.511	-0.070
50	6	384.228	388.009	-3.781
50	7	387.893	388.011	-0.118
50	8	386.673	392.900	-6.227
50	9	386.663	386.786	-0.123
50	10	385.441	384.352	1.089
100	B011	385.441	386.923	-1.482
100	B012	386.660	390.586	-3.926
100	B013	389.105	390.588	-1.483
100	B014	387.888	390.589	-2.701
100	B015	384.228	386.927	-2.699
	Max	389.105	394.060	1.089
	Average	386.301	388.679	-2.378
	Min	384.228	384.352	-7.387
	Std Dev	1.434	2.589	2.316

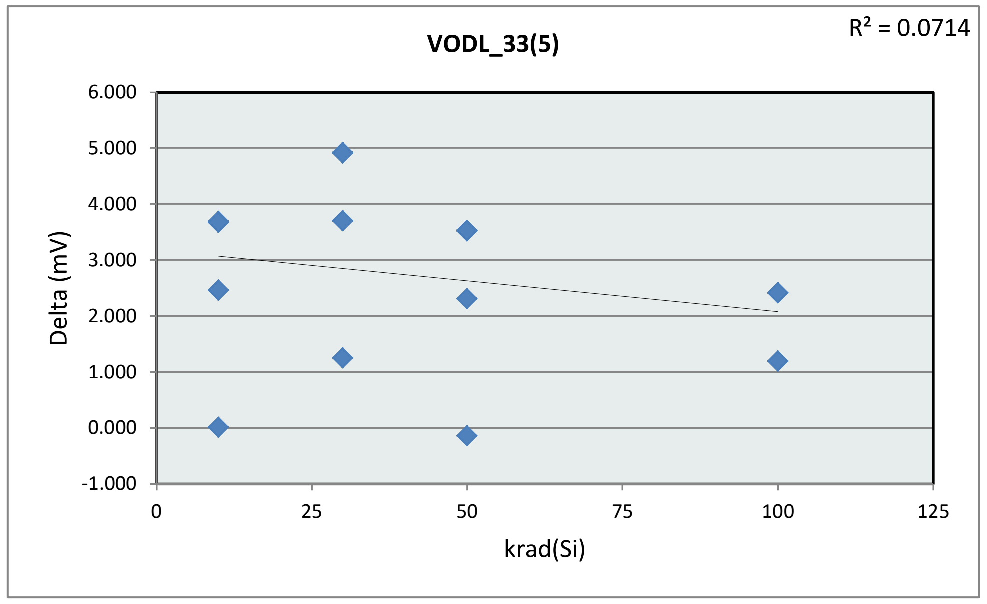


	VODH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	385.464	385.511	384.352	386.923
Average	388.655	388.928	388.012	389.123
Max	392.827	394.060	392.900	390.589
UL	430.000	430.000	430.000	430.000

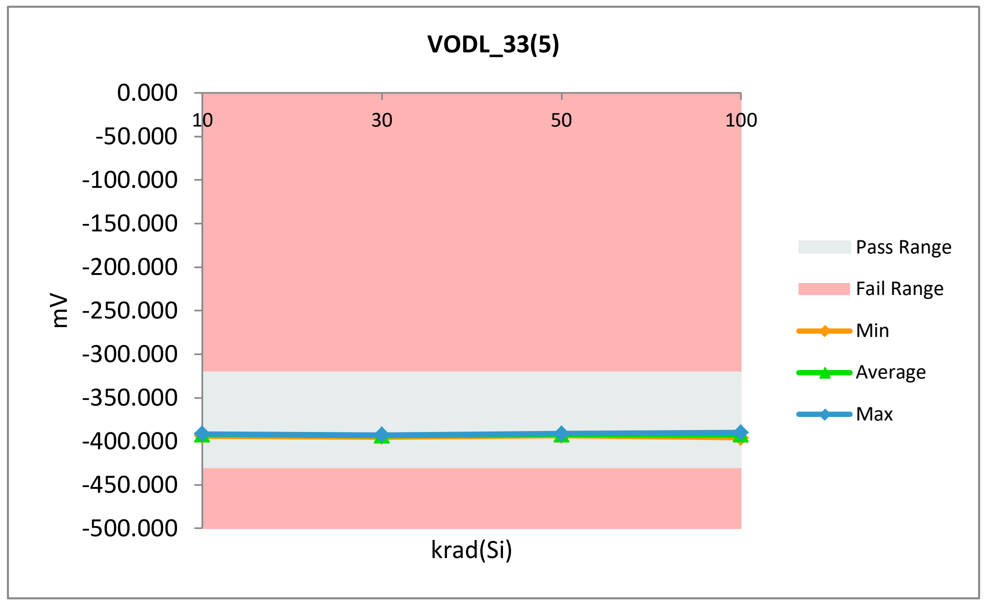


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-390.100	-392.561	2.461
10	7	-388.879	-391.334	2.455
10	8	-390.099	-393.789	3.690
10	9	-391.329	-391.334	0.005
10	10	-388.887	-392.561	3.674
30	6	-390.100	-393.798	3.698
30	7	-388.879	-392.577	3.698
30	8	-390.099	-395.016	4.917
30	9	-391.329	-392.578	1.249
30	10	-388.887	-393.793	4.906
50	6	-390.100	-392.407	2.307
50	7	-388.879	-392.405	3.526
50	8	-390.099	-393.623	3.524
50	9	-391.329	-391.187	-0.142
50	10	-388.887	-392.400	3.513
100	B011	-388.887	-391.298	2.411
100	B012	-387.668	-390.078	2.410
100	B013	-394.994	-396.185	1.191
100	B014	-392.547	-393.740	1.193
100	B015	-390.100	-392.515	2.415
	Max	-387.668	-390.078	4.917
	Average	-390.104	-392.759	2.655
	Min	-394.994	-396.185	-0.142
	Std Dev	1.634	1.418	1.418



	VODL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-393.789	-395.016	-393.623	-396.185
Average	-392.316	-393.552	-392.404	-392.763
Max	-391.334	-392.577	-391.187	-390.078
UL	-320.000	-320.000	-320.000	-320.000



LDR UnBiased TID Report
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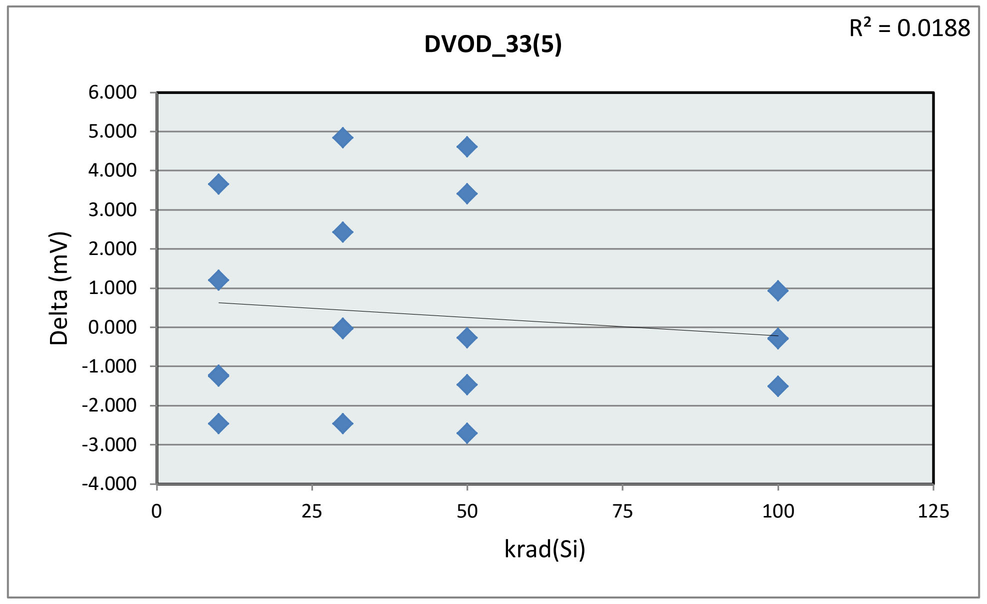
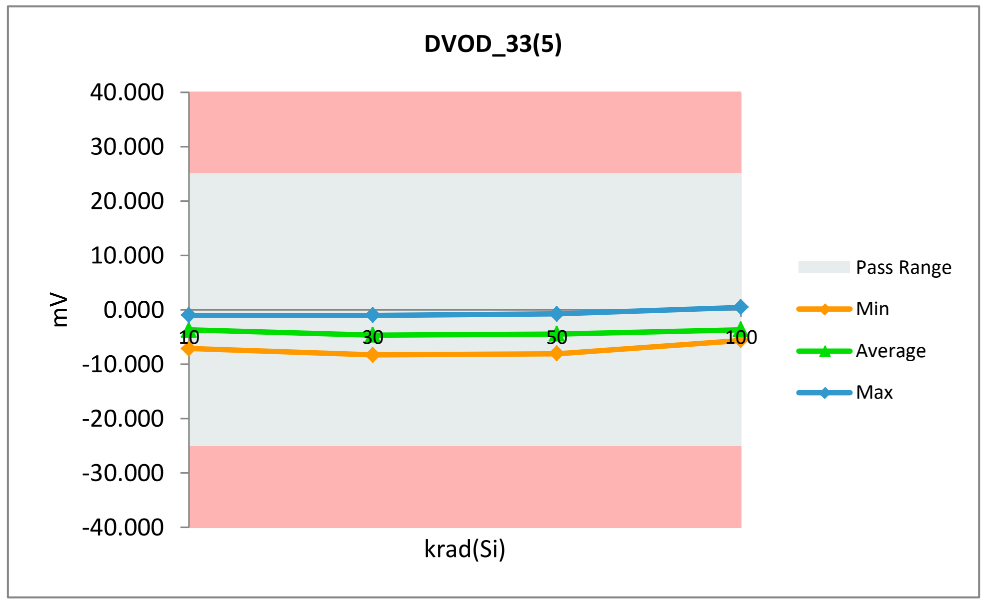
		DVOD_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-5.873	-4.643	-1.230
10	7	-0.986	-2.189	1.203
10	8	-3.426	-0.961	-2.465
10	9	-4.666	-3.416	-1.250
10	10	-3.446	-7.097	3.651
30	6	-5.873	-5.850	-0.023
30	7	-0.986	-3.406	2.420
30	8	-3.426	-0.955	-2.471
30	9	-4.666	-4.630	-0.036
30	10	-3.446	-8.283	4.837
50	6	-5.873	-4.398	-1.475
50	7	-0.986	-4.395	3.409
50	8	-3.426	-0.723	-2.703
50	9	-4.666	-4.401	-0.265
50	10	-3.446	-8.048	4.602
100	B011	-3.446	-4.376	0.930
100	B012	-1.009	0.508	-1.517
100	B013	-5.889	-5.597	-0.292
100	B014	-4.660	-3.150	-1.510
100	B015	-5.873	-5.588	-0.285
	Max	-0.986	0.508	4.837
	Average	-3.803	-4.080	0.277
	Min	-5.889	-8.283	-2.703
	Std Dev	1.732	2.388	2.359



	DVOD_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-7.097	-8.283	-8.048	-5.597
Average	-3.661	-4.625	-4.393	-3.641
Max	-0.961	-0.955	-0.723	0.508
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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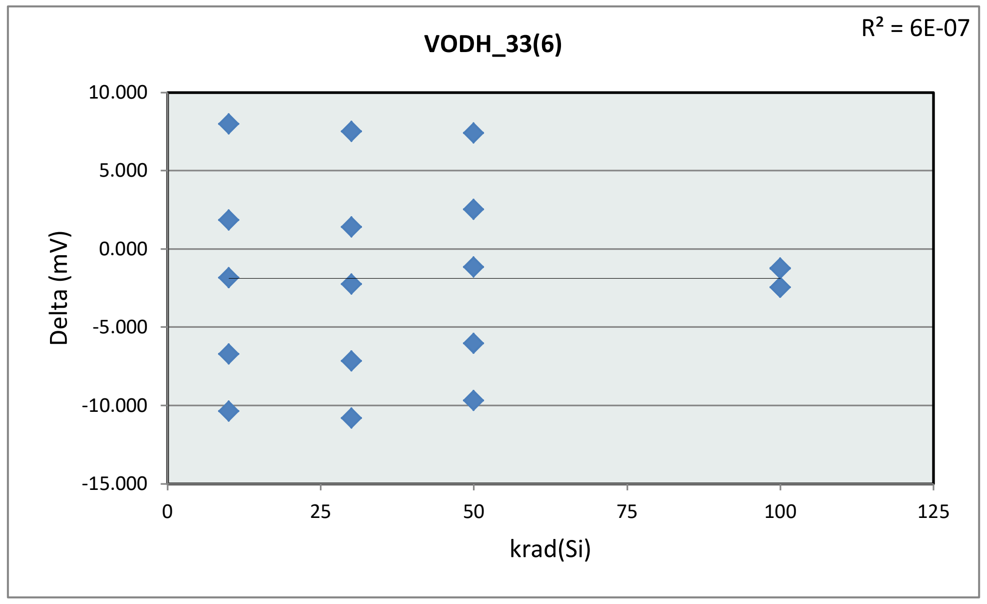
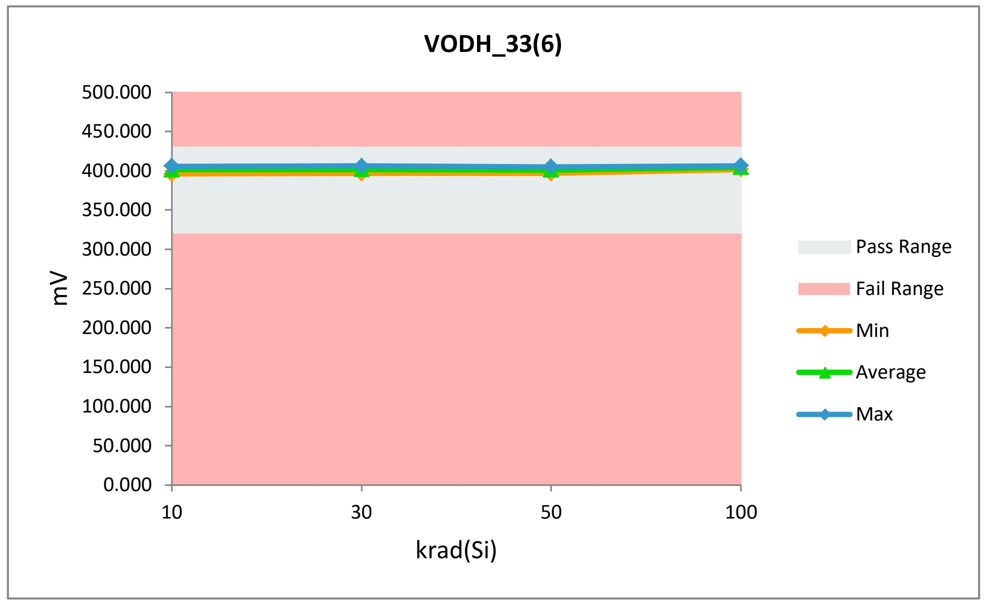
		VODH_33(6)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	402.735	400.897	1.838
10	7	403.949	395.991	7.958
10	8	403.953	405.802	-1.849
10	9	394.190	400.896	-6.706
10	10	392.967	403.351	-10.384
30	6	402.735	401.342	1.393
30	7	403.949	396.467	7.482
30	8	403.953	406.218	-2.265
30	9	394.190	401.340	-7.150
30	10	392.967	403.788	-10.821
50	6	402.735	400.228	2.507
50	7	403.949	396.572	7.377
50	8	403.953	405.105	-1.152
50	9	394.190	400.225	-6.035
50	10	392.967	402.672	-9.705
100	B011	402.721	405.195	-2.474
100	B012	399.070	401.547	-2.477
100	B013	402.719	403.970	-1.251
100	B014	405.166	406.416	-1.250
100	B015	402.735	405.212	-2.477
	Max	405.166	406.416	7.958
	Average	400.290	402.162	-1.872
	Min	392.967	395.991	-10.821
	Std Dev	4.667	3.218	5.611



	VODH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	395.991	396.467	396.572	401.547
Average	401.387	401.831	400.960	404.468
Max	405.802	406.218	405.105	406.416
UL	430.000	430.000	430.000	430.000



LDR UnBiased TID Report
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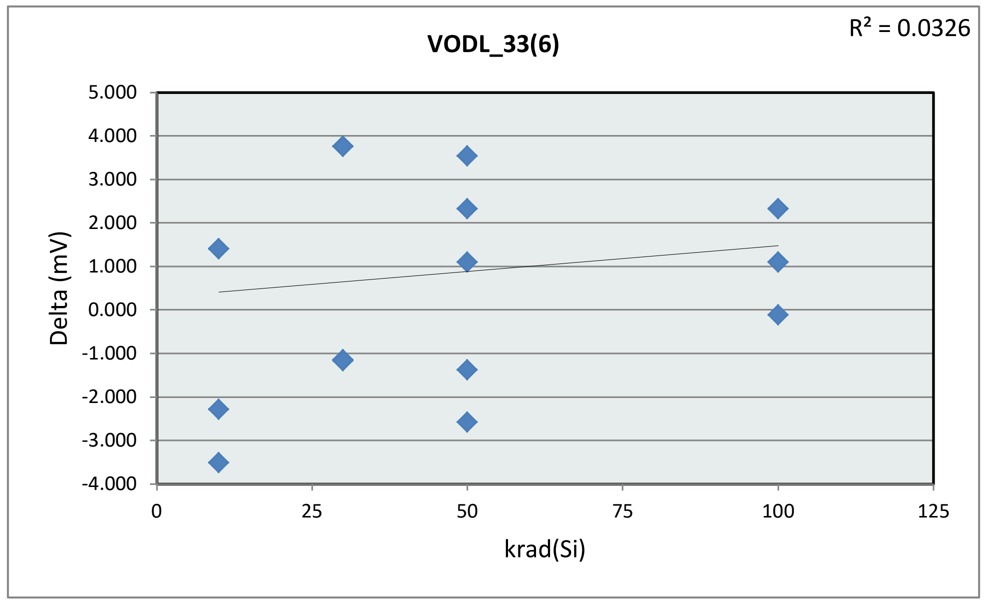
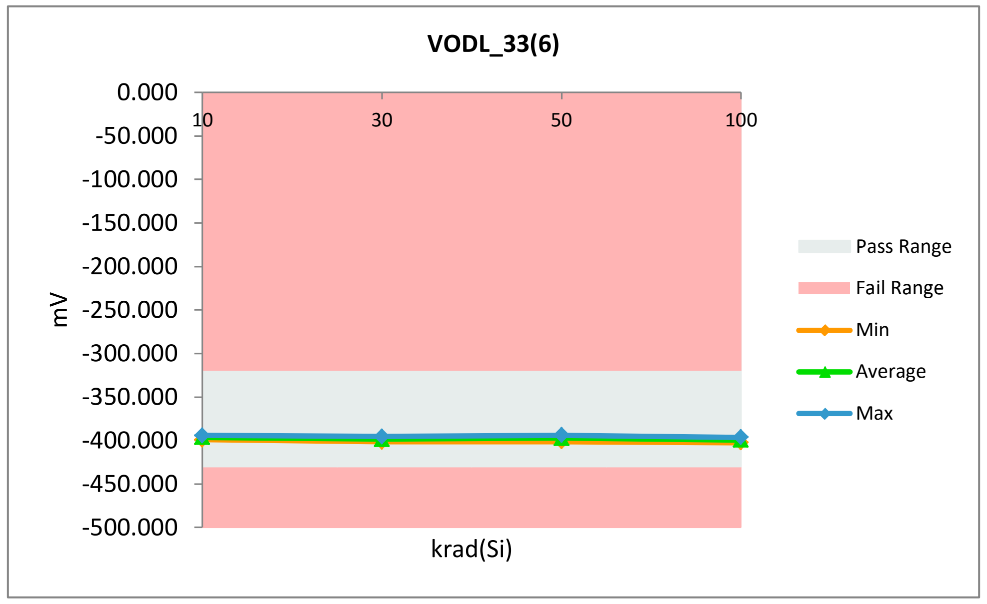
	VODL_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-396.588	-394.307	-2.281
10	7	-399.042	-395.531	-3.511
10	8	-397.815	-399.218	1.403
10	9	-395.356	-396.762	1.406
10	10	-394.134	-395.534	1.400
30	6	-396.588	-395.443	-1.145
30	7	-399.042	-397.876	-1.166
30	8	-397.815	-401.567	3.752
30	9	-395.356	-399.114	3.758
30	10	-394.134	-397.887	3.753
50	6	-396.588	-394.008	-2.580
50	7	-399.042	-397.664	-1.378
50	8	-397.815	-401.349	3.534
50	9	-395.356	-396.455	1.099
50	10	-394.134	-396.452	2.318
100	B011	-400.268	-402.590	2.322
100	B012	-394.144	-396.463	2.319
100	B013	-399.049	-400.149	1.100
100	B014	-400.270	-400.148	-0.122
100	B015	-396.588	-397.686	1.098
	Max	-394.134	-394.008	3.758
	Average	-396.956	-397.810	0.854
	Min	-400.270	-402.590	-3.511
	Std Dev	2.073	2.444	2.232



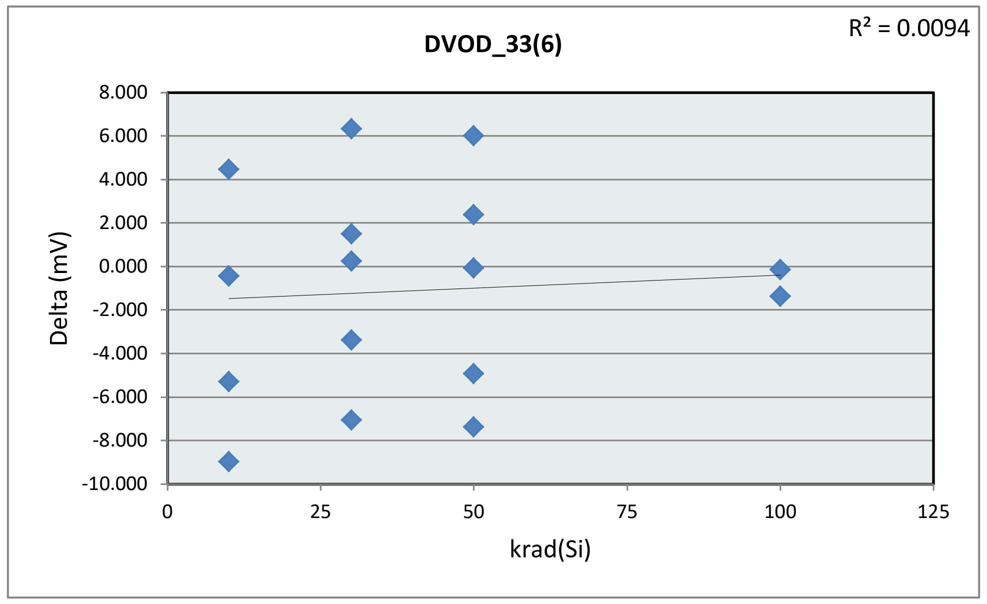
	VODL_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-399.218	-401.567	-401.349	-402.590
Average	-396.270	-398.377	-397.186	-399.407
Max	-394.307	-395.443	-394.008	-396.463
UL	-320.000	-320.000	-320.000	-320.000



LDR UnBiased TID Report
SN55LVCP22A-SP

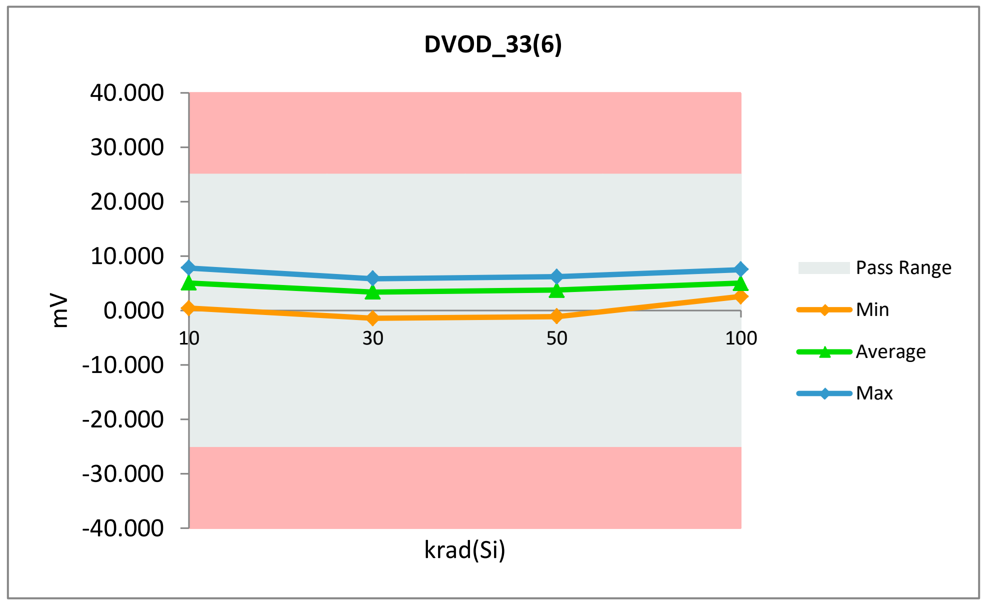
	DVOD_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	6.147	6.590	-0.443
10	7	4.908	0.459	4.449
10	8	6.138	6.584	-0.446
10	9	-1.166	4.135	-5.301
10	10	-1.168	7.818	-8.986
30	6	6.147	5.899	0.248
30	7	4.908	-1.409	6.317
30	8	6.138	4.651	1.487
30	9	-1.166	2.227	-3.393
30	10	-1.168	5.901	-7.069
50	6	6.147	6.220	-0.073
50	7	4.908	-1.093	6.001
50	8	6.138	3.756	2.382
50	9	-1.166	3.770	-4.936
50	10	-1.168	6.220	-7.388
100	B011	2.453	2.604	-0.151
100	B012	4.926	5.084	-0.158
100	B013	3.669	3.821	-0.152
100	B014	4.896	6.268	-1.372
100	B015	6.147	7.527	-1.380
	Max	6.147	7.818	6.317
	Average	3.333	4.352	-1.018
	Min	-1.168	-1.409	-8.986
	Std Dev	3.163	2.663	4.208



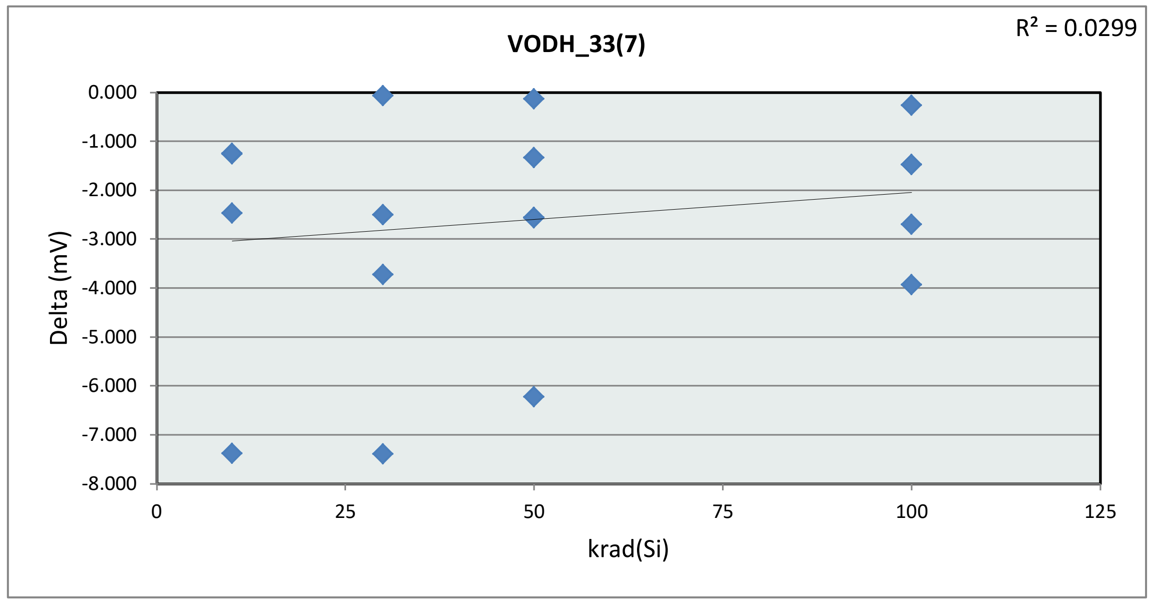
	DVOD_33(6)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.459	-1.409	-1.093	2.604
Average	5.117	3.454	3.775	5.061
Max	7.818	5.901	6.220	7.527
UL	25.000	25.000	25.000	25.000

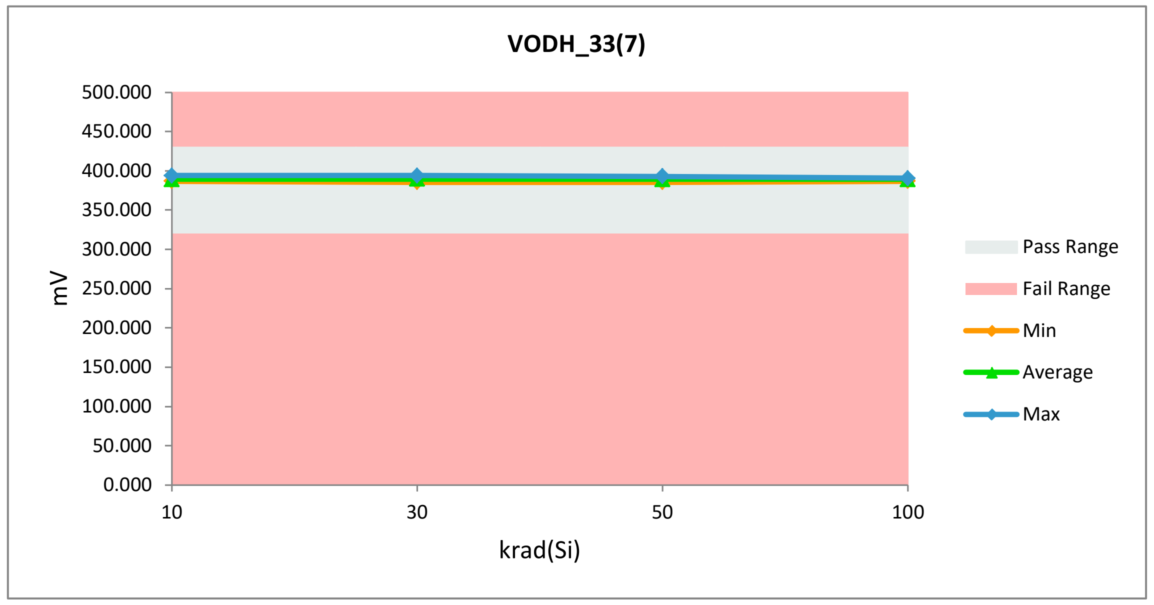


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODH_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		430	430	
Min Limit		320	320	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	385.445	387.918	-2.473
10	7	387.889	389.146	-1.257
10	8	386.668	394.054	-7.386
10	9	386.659	387.918	-1.259
10	10	385.437	386.691	-1.254
30	6	385.445	389.167	-3.722
30	7	387.889	390.390	-2.501
30	8	386.668	394.057	-7.389
30	9	386.659	389.167	-2.508
30	10	385.437	385.508	-0.071
50	6	385.445	386.784	-1.339
50	7	387.889	390.449	-2.560
50	8	386.668	392.896	-6.228
50	9	386.659	389.225	-2.566
50	10	385.437	385.569	-0.132
100	B011	385.437	388.142	-2.705
100	B012	386.656	390.584	-3.928
100	B013	389.100	389.364	-0.264
100	B014	389.105	390.587	-1.482
100	B015	385.445	386.925	-1.480
	Max	389.105	394.057	-0.071
	Average	386.602	389.227	-2.625
	Min	385.437	385.508	-7.389
	Std Dev	1.220	2.473	2.171



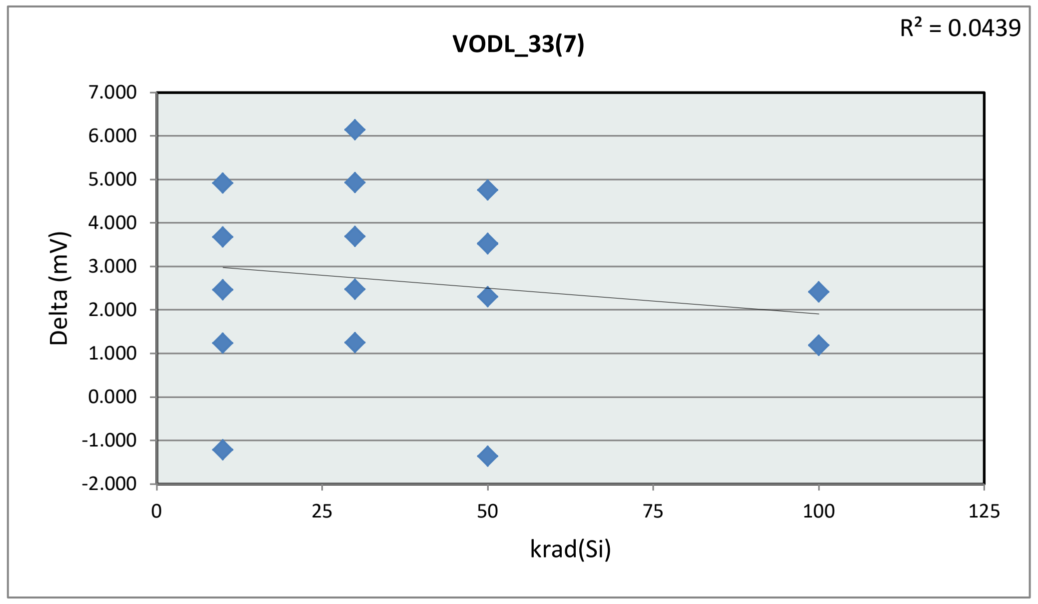
	VODH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	386.691	385.508	385.569	386.925
Average	389.145	389.658	388.985	389.120
Max	394.054	394.057	392.896	390.587
UL	430.000	430.000	430.000	430.000



LDR UnBiased TID Report
SN55LVCP22A-SP

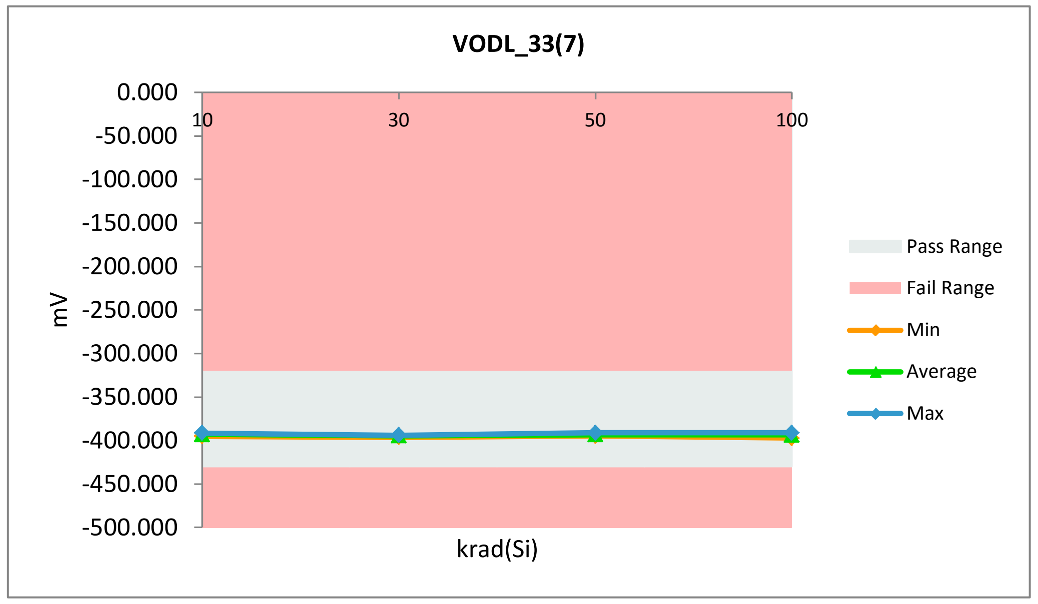
	VODL_33(7)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-391.327	-392.561	1.234
10	7	-390.104	-392.561	2.457
10	8	-390.103	-395.016	4.913
10	9	-392.555	-391.334	-1.221
10	10	-390.113	-393.789	3.676
30	6	-391.327	-393.801	2.474
30	7	-390.104	-395.022	4.918
30	8	-390.103	-396.240	6.137
30	9	-392.555	-393.803	1.248
30	10	-390.113	-393.797	3.684
50	6	-391.327	-393.632	2.305
50	7	-390.104	-393.631	3.527
50	8	-390.103	-394.848	4.745
50	9	-392.555	-391.191	-1.364
50	10	-390.113	-393.625	3.512
100	B011	-388.892	-391.301	2.409
100	B012	-390.115	-391.302	1.187
100	B013	-396.220	-397.408	1.188
100	B014	-393.773	-394.963	1.190
100	B015	-391.327	-393.739	2.412
	Max	-388.892	-391.191	6.137
	Average	-391.147	-393.678	2.532
	Min	-396.220	-397.408	-1.364
	Std Dev	1.695	1.664	1.946



	VODL_33(7)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	-320	mV
Min Limit	-430	mV

krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-395.016	-396.240	-394.848	-397.408
Average	-393.052	-394.533	-393.385	-393.743
Max	-391.334	-393.797	-391.191	-391.301
UL	-320.000	-320.000	-320.000	-320.000



LDR UnBiased TID Report
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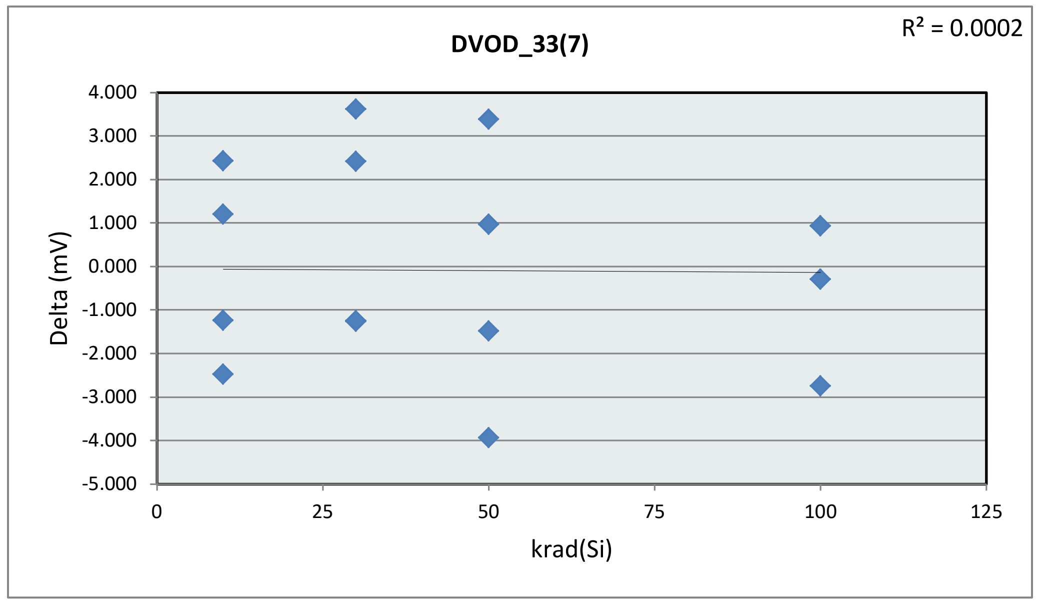
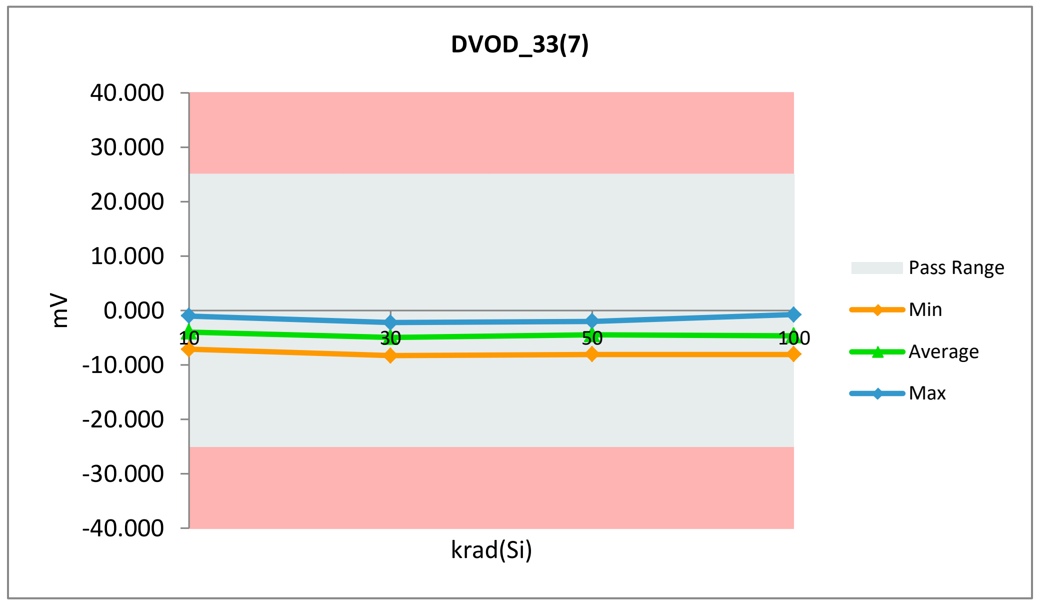
		DVOD_33(7)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-5.882	-4.643	-1.239
10	7	-2.215	-3.416	1.201
10	8	-3.435	-0.962	-2.473
10	9	-5.897	-3.416	-2.481
10	10	-4.676	-7.097	2.421
30	6	-5.882	-4.634	-1.248
30	7	-2.215	-4.632	2.417
30	8	-3.435	-2.183	-1.252
30	9	-5.897	-4.636	-1.261
30	10	-4.676	-8.289	3.613
50	6	-5.882	-6.848	0.966
50	7	-2.215	-3.182	0.967
50	8	-3.435	-1.952	-1.483
50	9	-5.897	-1.966	-3.931
50	10	-4.676	-8.056	3.380
100	B011	-3.455	-3.159	-0.296
100	B012	-3.459	-0.718	-2.741
100	B013	-7.119	-8.045	0.926
100	B014	-4.668	-4.376	-0.292
100	B015	-5.882	-6.814	0.932
	Max	-2.215	-0.718	3.613
	Average	-4.545	-4.451	-0.094
	Min	-7.119	-8.289	-3.931
	Std Dev	1.481	2.387	2.114



	DVOD_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-7.097	-8.289	-8.056	-8.045
Average	-3.907	-4.875	-4.401	-4.622
Max	-0.962	-2.183	-1.952	-0.718
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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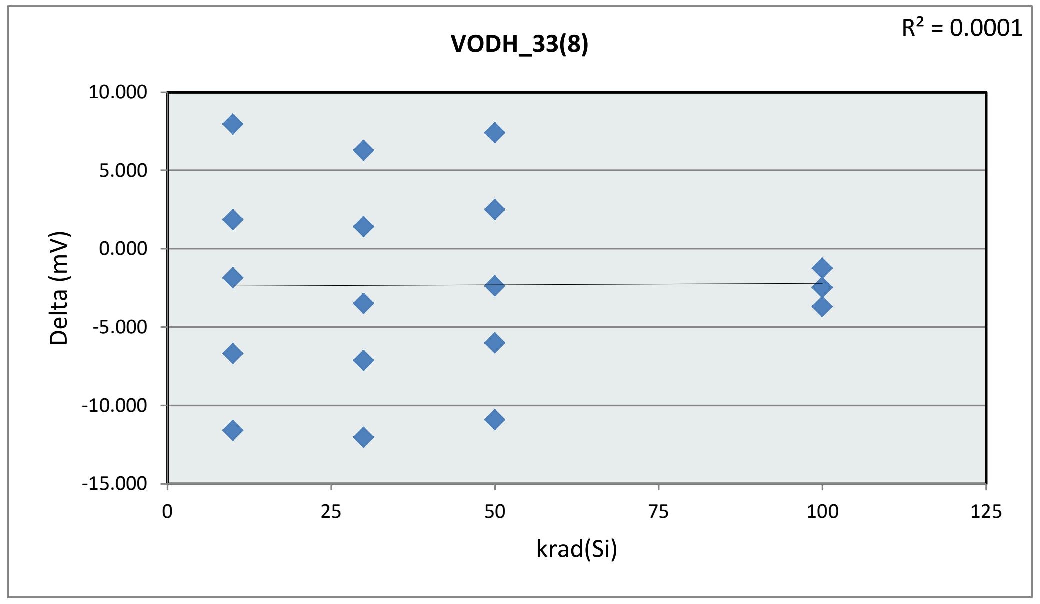
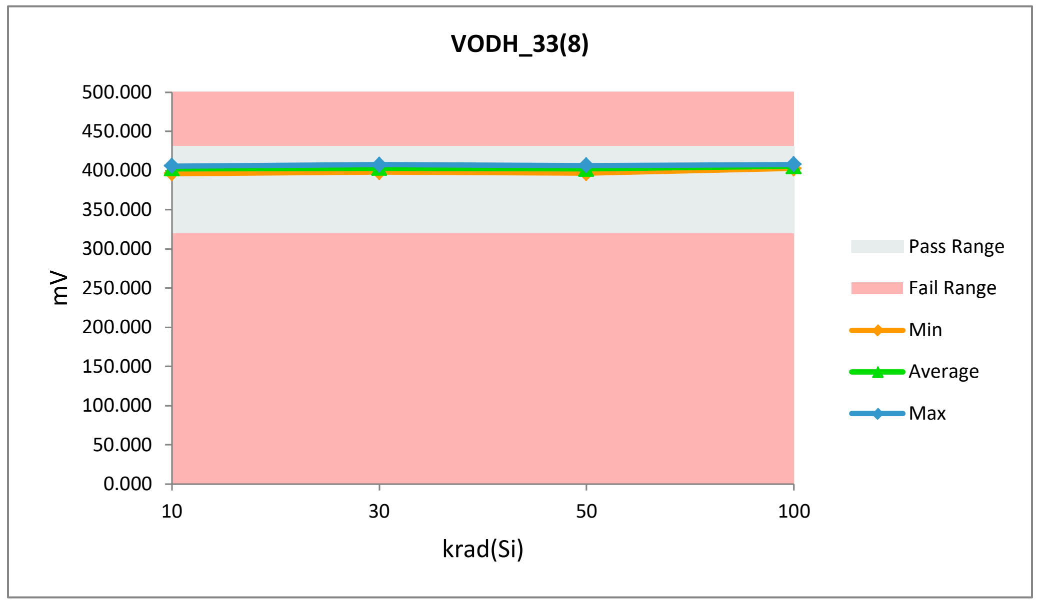
	VODH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	403.953	402.123	1.830
10	7	403.944	395.989	7.955
10	8	403.948	405.801	-1.853
10	9	395.406	402.122	-6.716
10	10	392.960	404.577	-11.617
30	6	403.953	402.558	1.395
30	7	403.944	397.681	6.263
30	8	403.948	407.433	-3.485
30	9	395.406	402.554	-7.148
30	10	392.960	405.002	-12.042
50	6	403.953	401.443	2.510
50	7	403.944	396.564	7.380
50	8	403.948	406.321	-2.373
50	9	395.406	401.442	-6.036
50	10	392.960	403.888	-10.928
100	B011	403.939	406.410	-2.471
100	B012	399.064	402.762	-3.698
100	B013	403.935	405.187	-1.252
100	B014	405.160	407.631	-2.471
100	B015	403.953	405.206	-1.253
	Max	405.160	407.631	7.955
	Average	400.834	403.135	-2.301
	Min	392.960	395.989	-12.042
	Std Dev	4.660	3.355	5.826

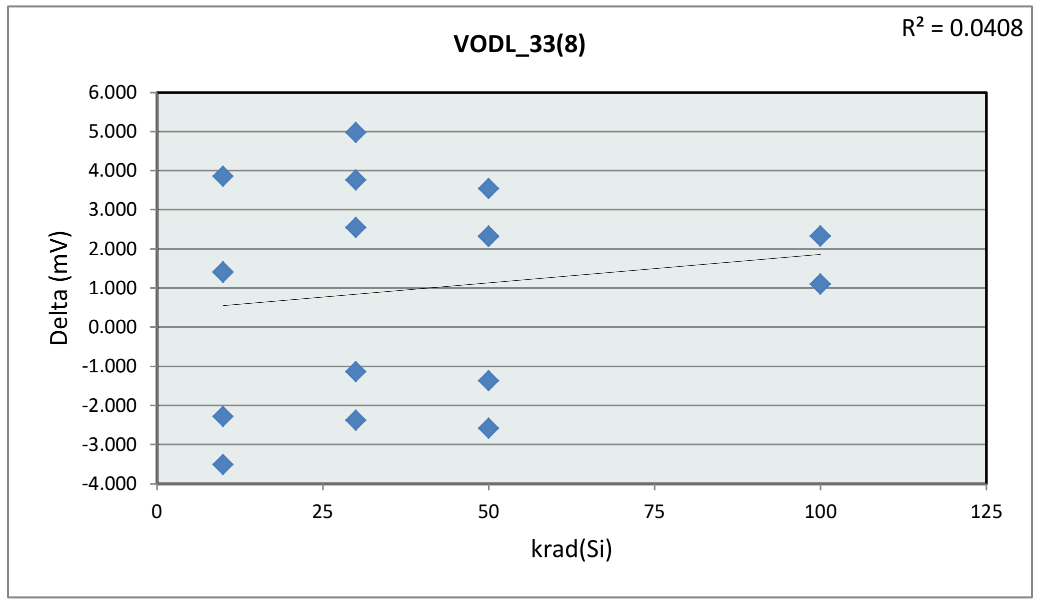


	VODH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	395.989	397.681	396.564	402.762
Average	402.122	403.046	401.932	405.439
Max	405.801	407.433	406.321	407.631
UL	430.000	430.000	430.000	430.000

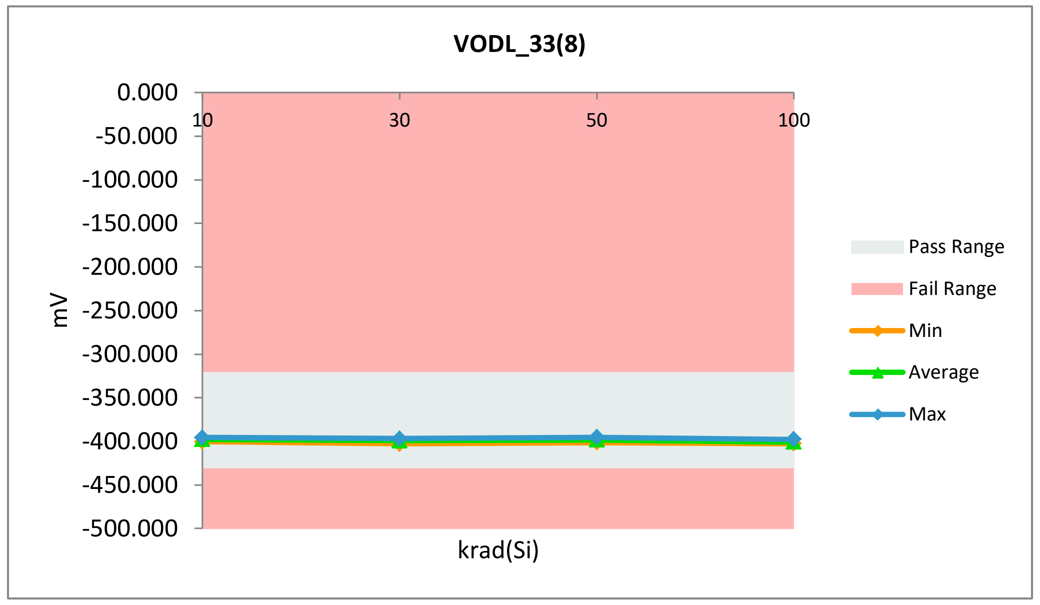


LDR UnBiased TID Report
SN55LVCP22A-SP

		VODL_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-397.816	-395.535	-2.281
10	7	-400.268	-396.760	-3.508
10	8	-399.043	-400.447	1.404
10	9	-396.584	-397.991	1.407
10	10	-394.141	-397.990	3.849
30	6	-397.816	-396.671	-1.145
30	7	-400.268	-397.883	-2.385
30	8	-399.043	-402.797	3.754
30	9	-396.584	-399.121	2.537
30	10	-394.141	-399.117	4.976
50	6	-397.816	-395.236	-2.580
50	7	-400.268	-398.893	-1.375
50	8	-399.043	-401.357	2.314
50	9	-396.584	-398.904	2.320
50	10	-394.141	-397.679	3.538
100	B011	-401.496	-402.598	1.102
100	B012	-395.372	-397.692	2.320
100	B013	-400.277	-401.378	1.101
100	B014	-399.052	-401.376	2.324
100	B015	-397.816	-400.136	2.320
	Max	-394.141	-395.236	4.976
	Average	-397.878	-398.978	1.100
	Min	-401.496	-402.797	-3.508
	Std Dev	2.232	2.188	2.458



	VODL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-400.447	-402.797	-401.357	-402.598
Average	-397.745	-399.118	-398.414	-400.636
Max	-395.535	-396.671	-395.236	-397.692
UL	-320.000	-320.000	-320.000	-320.000



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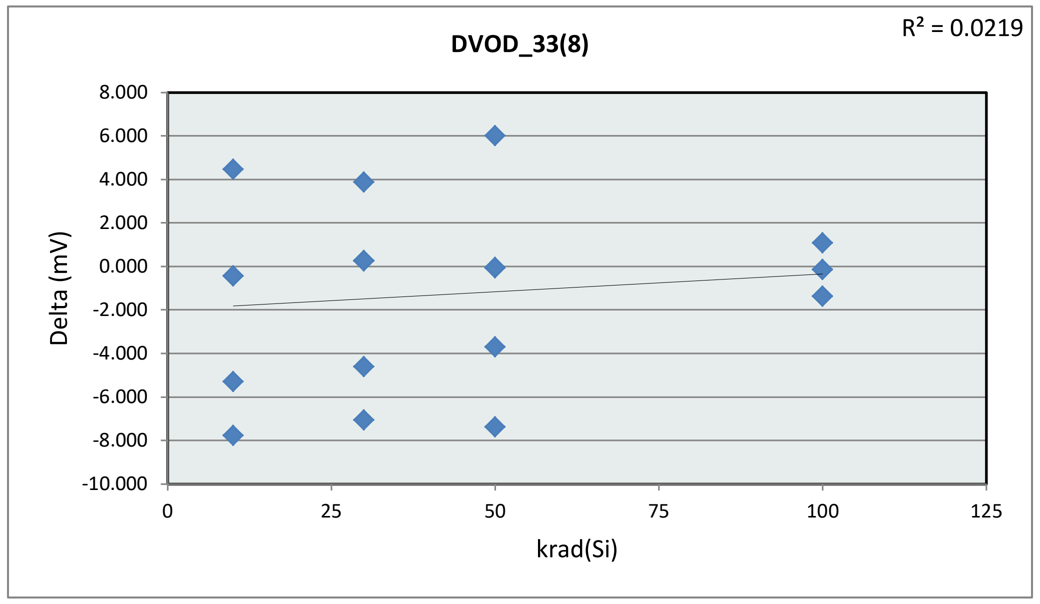
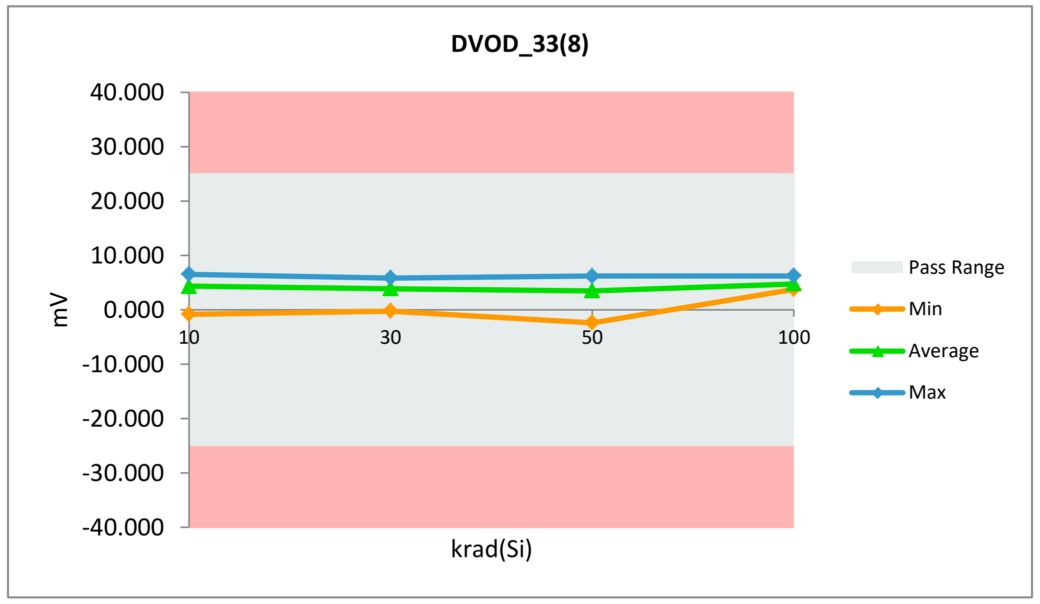
		DVOD_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	6.137	6.588	-0.451
10	7	3.676	-0.771	4.447
10	8	4.905	5.353	-0.448
10	9	-1.178	4.131	-5.309
10	10	-1.181	6.587	-7.768
30	6	6.137	5.886	0.251
30	7	3.676	-0.203	3.879
30	8	4.905	4.636	0.269
30	9	-1.178	3.433	-4.611
30	10	-1.181	5.885	-7.066
50	6	6.137	6.207	-0.070
50	7	3.676	-2.328	6.004
50	8	4.905	4.964	-0.059
50	9	-1.178	2.538	-3.716
50	10	-1.181	6.210	-7.391
100	B011	2.442	3.812	-1.370
100	B012	3.693	5.071	-1.378
100	B013	3.657	3.809	-0.152
100	B014	6.109	6.255	-0.146
100	B015	6.137	5.071	1.066
	Max	6.137	6.588	6.004
	Average	2.956	4.157	-1.201
	Min	-1.181	-2.328	-7.768
	Std Dev	2.967	2.548	3.809



	DVOD_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.771	-0.203	-2.328	3.809
Average	4.377	3.927	3.518	4.804
Max	6.588	5.886	6.210	6.255
UL	25.000	25.000	25.000	25.000



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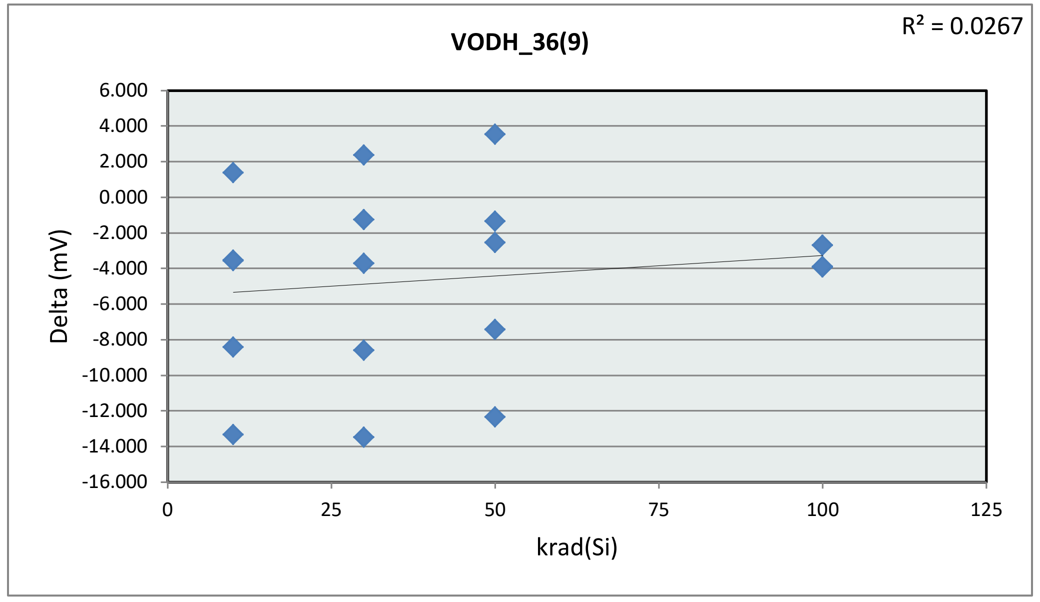
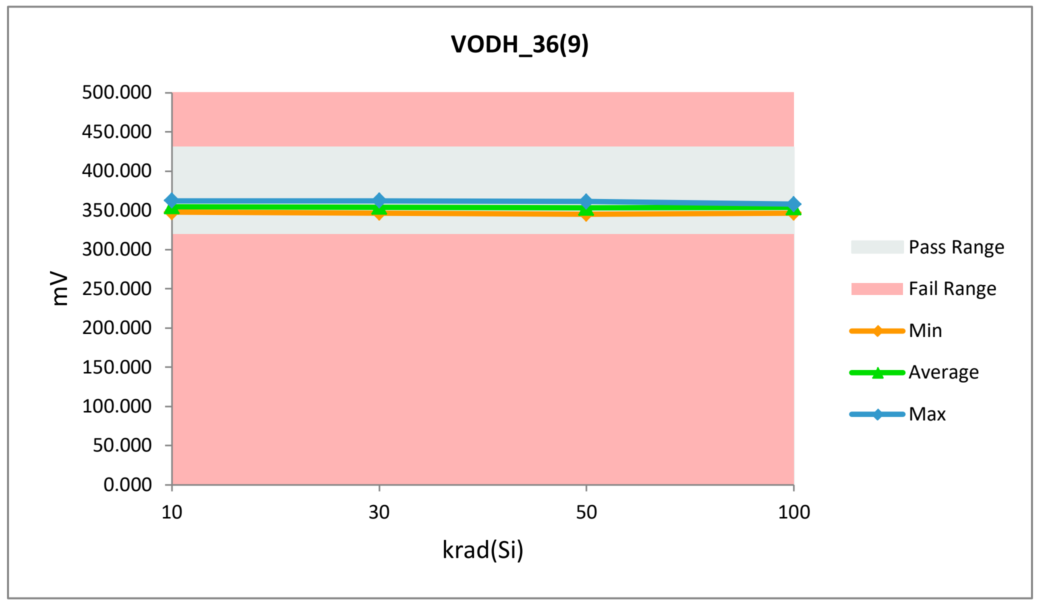
	VODH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	342.687	351.103	-8.416
10	7	352.459	356.012	-3.553
10	8	348.794	362.148	-13.354
10	9	352.450	356.012	-3.562
10	10	348.786	347.422	1.364
30	6	342.687	351.294	-8.607
30	7	352.459	353.738	-1.279
30	8	348.794	362.291	-13.497
30	9	352.450	356.179	-3.729
30	10	348.786	346.413	2.373
50	6	342.687	350.134	-7.447
50	7	352.459	355.021	-2.562
50	8	348.794	361.131	-12.337
50	9	352.450	353.798	-1.348
50	10	348.786	345.256	3.530
100	B011	350.008	353.929	-3.921
100	B012	352.447	356.371	-3.924
100	B013	354.892	357.594	-2.702
100	B014	351.232	353.931	-2.699
100	B015	342.687	346.603	-3.916
	Max	354.892	362.291	3.530
	Average	349.340	353.819	-4.479
	Min	342.687	345.256	-13.497
	Std Dev	3.850	5.029	4.821



	VODH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	347.422	346.413	345.256	346.603
Average	354.539	353.983	353.068	353.686
Max	362.148	362.291	361.131	357.594
UL	430.000	430.000	430.000	430.000



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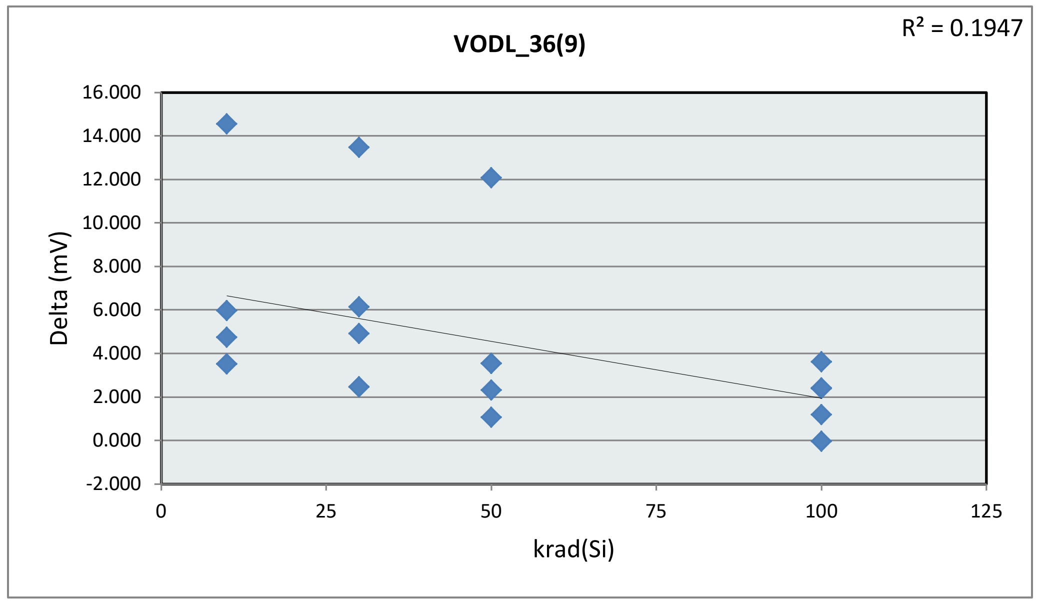
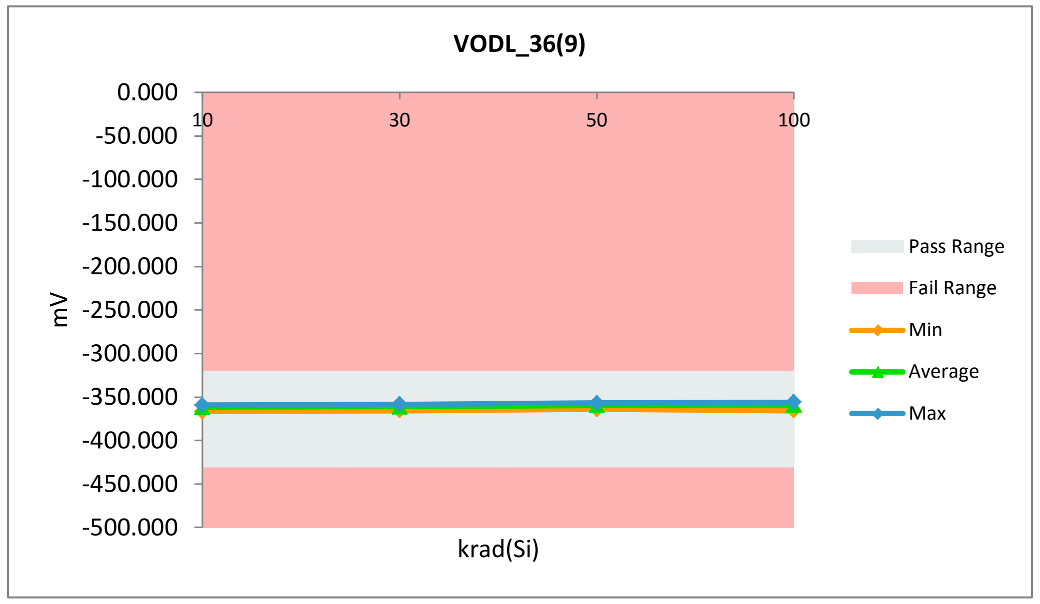
	VODL_36(9)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	mV	mV	
Max Limit	-320	-320	
Min Limit	-430	-430	

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-353.477	-359.428	5.951
10	7	-355.917	-360.655	4.738
10	8	-352.254	-366.791	14.537
10	9	-358.368	-361.882	3.514
10	10	-355.926	-359.428	3.502
30	6	-353.477	-359.607	6.130
30	7	-355.917	-360.828	4.911
30	8	-352.254	-365.711	13.457
30	9	-358.368	-360.830	2.462
30	10	-355.926	-358.382	2.456
50	6	-353.477	-357.003	3.526
50	7	-355.917	-359.444	3.527
50	8	-352.254	-364.326	12.072
50	9	-358.368	-360.668	2.300
50	10	-355.926	-356.996	1.070
100	B011	-355.927	-358.320	2.393
100	B012	-354.708	-358.322	3.614
100	B013	-364.476	-365.650	1.174
100	B014	-359.587	-359.540	-0.047
100	B015	-353.477	-355.873	2.396
	Max	-352.254	-355.873	14.537
	Average	-355.800	-360.484	4.684
	Min	-364.476	-366.791	-0.047
	Std Dev	2.991	3.036	4.057



	VODL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-366.791	-365.711	-364.326	-365.650
Average	-361.637	-361.072	-359.687	-359.541
Max	-359.428	-358.382	-356.996	-355.873
UL	-320.000	-320.000	-320.000	-320.000



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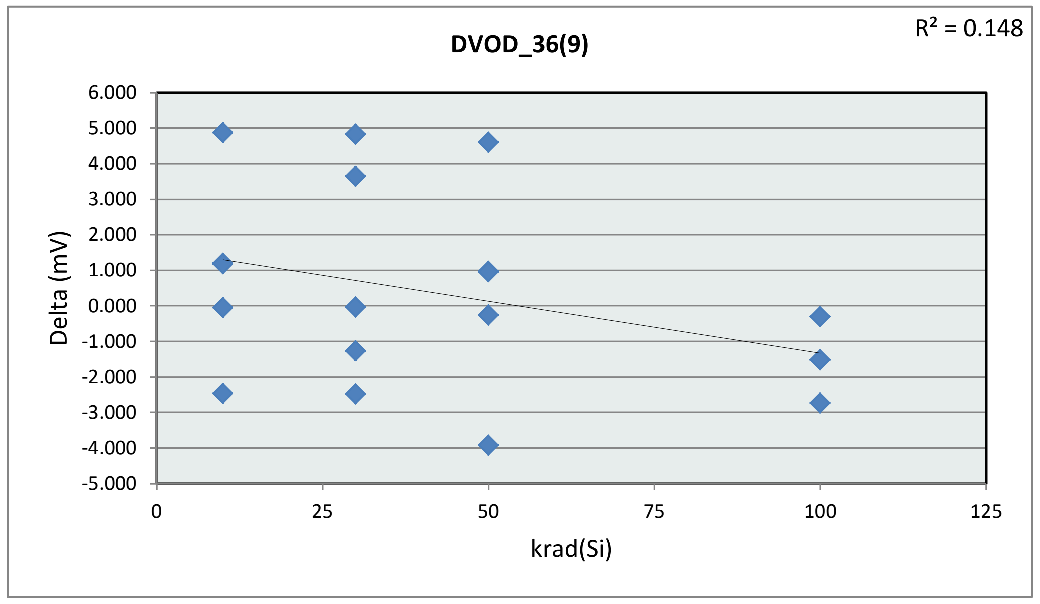
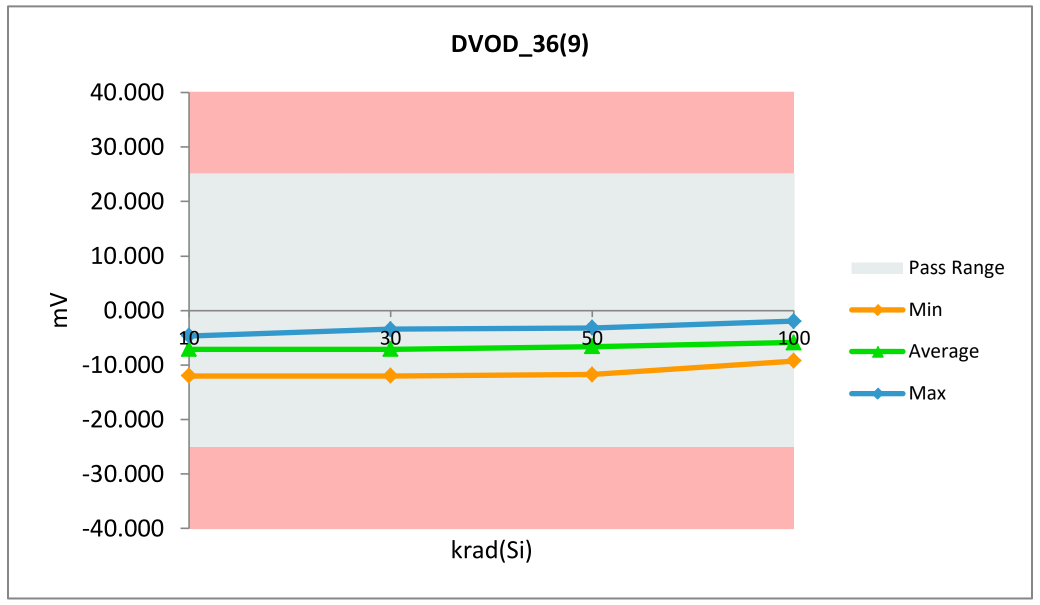
		DVOD_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.790	-8.324	-2.466
10	7	-3.457	-4.643	1.186
10	8	-3.460	-4.643	1.183
10	9	-5.918	-5.870	-0.048
10	10	-7.140	-12.006	4.866
30	6	-10.790	-8.314	-2.476
30	7	-3.457	-7.090	3.633
30	8	-3.460	-3.420	-0.040
30	9	-5.918	-4.651	-1.267
30	10	-7.140	-11.969	4.829
50	6	-10.790	-6.869	-3.921
50	7	-3.457	-4.423	0.966
50	8	-3.460	-3.195	-0.265
50	9	-5.918	-6.870	0.952
50	10	-7.140	-11.740	4.600
100	B011	-5.919	-4.391	-1.528
100	B012	-2.261	-1.951	-0.310
100	B013	-9.585	-8.056	-1.529
100	B014	-8.354	-5.609	-2.745
100	B015	-10.790	-9.270	-1.520
	Max	-2.261	-1.951	4.866
	Average	-6.460	-6.665	0.205
	Min	-10.790	-12.006	-3.921
	Std Dev	2.925	2.954	2.606



	DVOD_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-12.006	-11.969	-11.740	-9.270
Average	-7.097	-7.089	-6.619	-5.855
Max	-4.643	-3.420	-3.195	-1.951
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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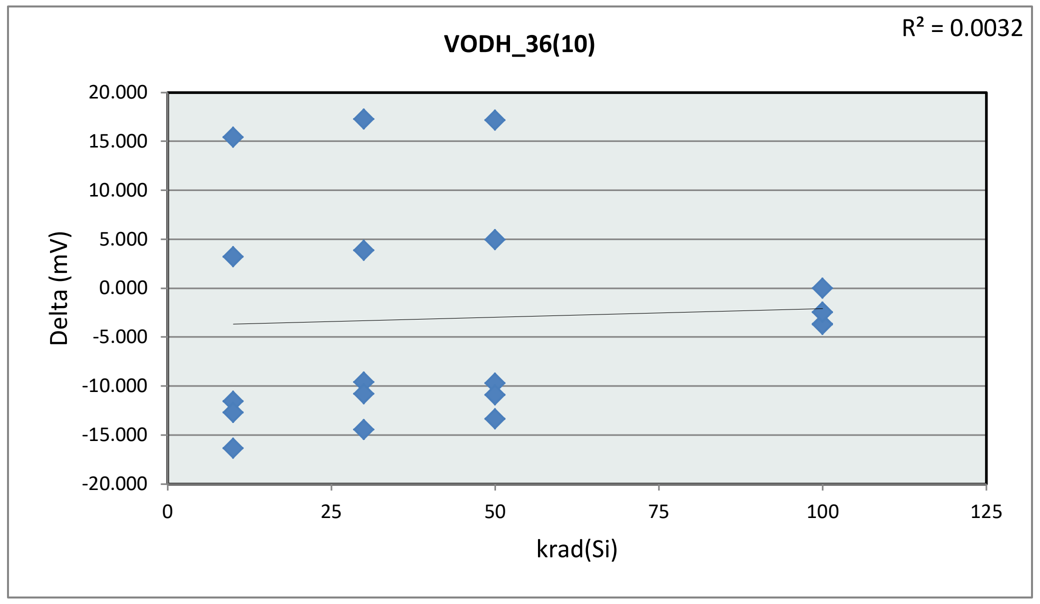
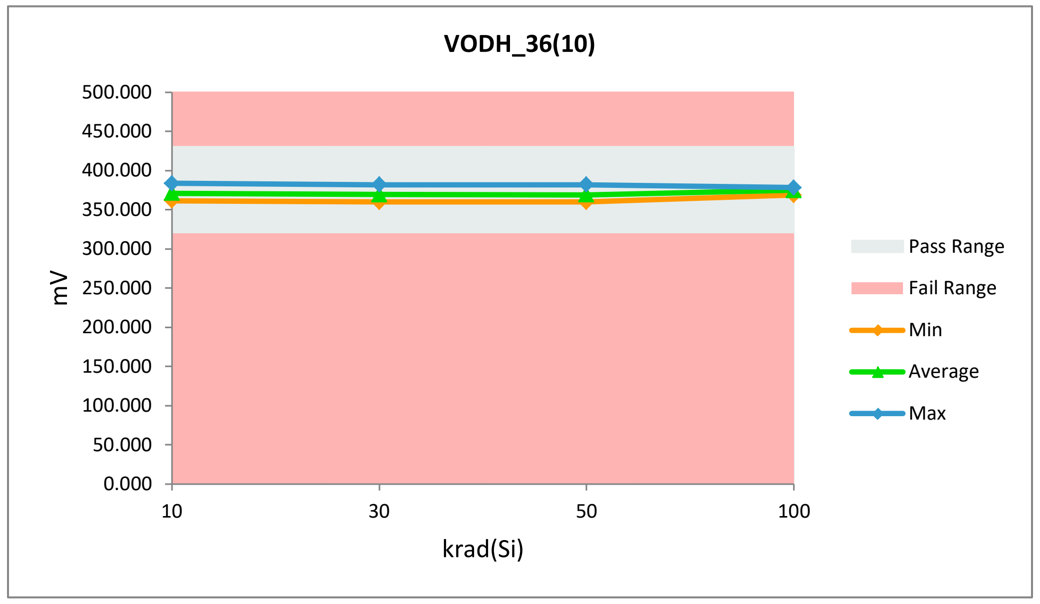
		VODH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	370.934	367.756	3.178
10	7	377.037	361.623	15.414
10	8	372.152	383.706	-11.554
10	9	357.500	370.210	-12.710
10	10	355.054	371.438	-16.384
30	6	370.934	367.091	3.843
30	7	377.037	359.770	17.267
30	8	372.152	381.745	-9.593
30	9	357.500	368.312	-10.812
30	10	355.054	369.537	-14.483
50	6	370.934	365.988	4.946
50	7	377.037	359.888	17.149
50	8	372.152	381.864	-9.712
50	9	357.500	368.429	-10.929
50	10	355.054	368.432	-13.378
100	B011	370.920	374.615	-3.695
100	B012	364.824	368.524	-3.700
100	B013	378.253	378.282	-0.029
100	B014	375.809	378.282	-2.473
100	B015	370.934	373.412	-2.478
	Max	378.253	383.706	17.267
	Average	367.939	370.945	-3.007
	Min	355.054	359.770	-16.384
	Std Dev	8.427	7.025	10.545



	VODH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	361.623	359.770	359.888	368.524
Average	370.947	369.291	368.920	374.623
Max	383.706	381.745	381.864	378.282
UL	430.000	430.000	430.000	430.000



LDR UnBiased TID Report
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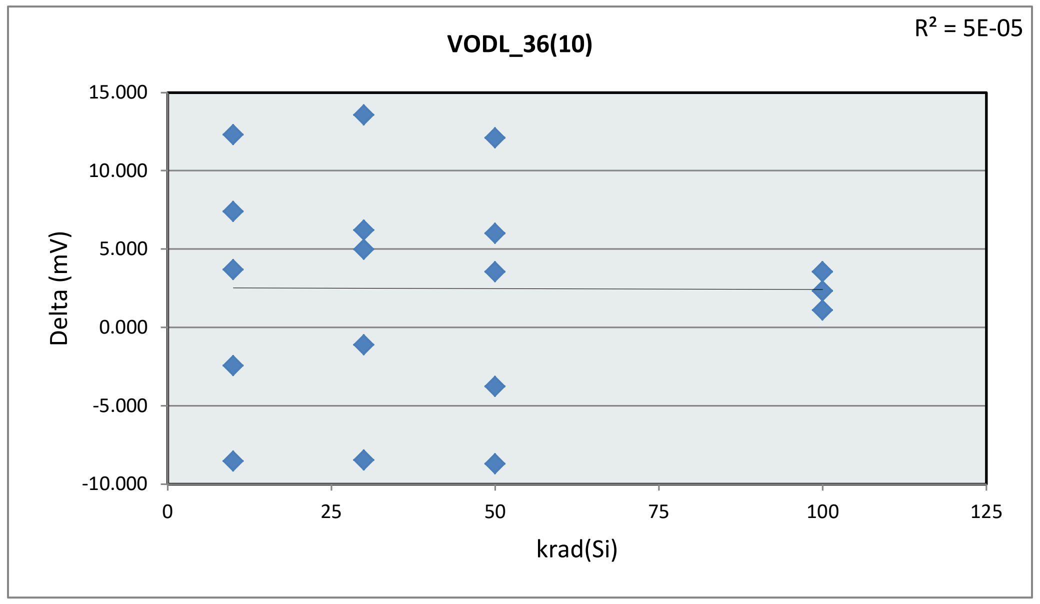
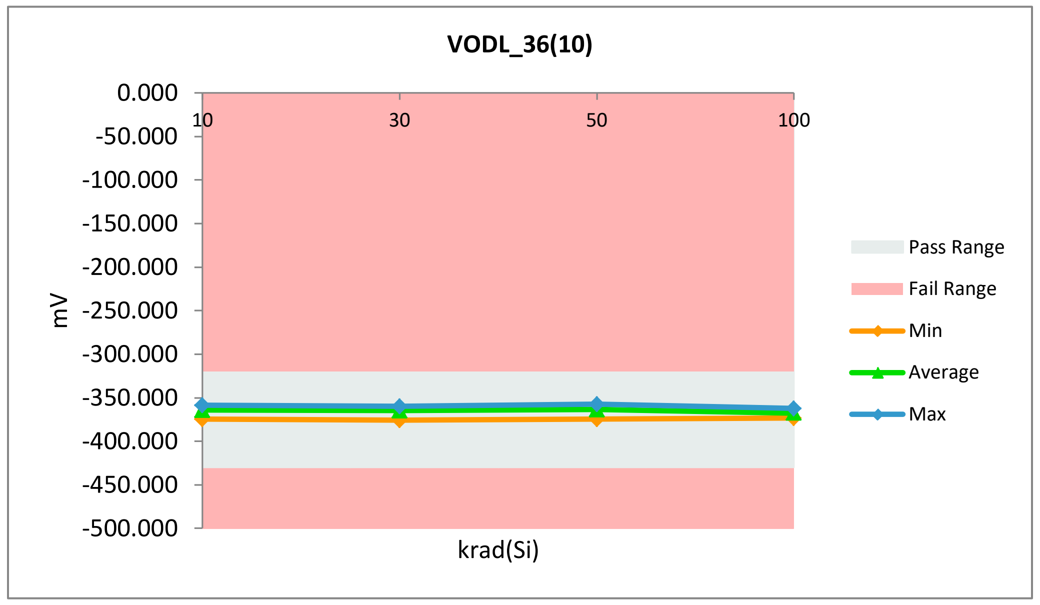
		VODL_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-361.168	-358.726	-2.442
10	7	-369.731	-361.178	-8.553
10	8	-362.393	-374.682	12.289
10	9	-358.713	-366.090	7.377
10	10	-356.270	-359.953	3.683
30	6	-361.168	-360.037	-1.131
30	7	-369.731	-361.249	-8.482
30	8	-362.393	-375.936	13.543
30	9	-358.713	-364.927	6.214
30	10	-356.270	-361.258	4.988
50	6	-361.168	-357.377	-3.791
50	7	-369.731	-361.033	-8.698
50	8	-362.393	-374.492	12.099
50	9	-358.713	-364.711	5.998
50	10	-356.270	-359.821	3.551
100	B011	-367.293	-370.845	3.552
100	B012	-358.722	-362.272	3.550
100	B013	-370.960	-373.289	2.329
100	B014	-367.293	-368.399	1.106
100	B015	-361.168	-363.494	2.326
	Max	-356.270	-357.377	13.543
	Average	-362.513	-364.988	2.475
	Min	-370.960	-375.936	-8.698
	Std Dev	4.895	5.901	6.561



	VODL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-374.682	-375.936	-374.492	-373.289
Average	-364.126	-364.681	-363.487	-367.660
Max	-358.726	-360.037	-357.377	-362.272
UL	-320.000	-320.000	-320.000	-320.000



LDR UnBiased TID Report
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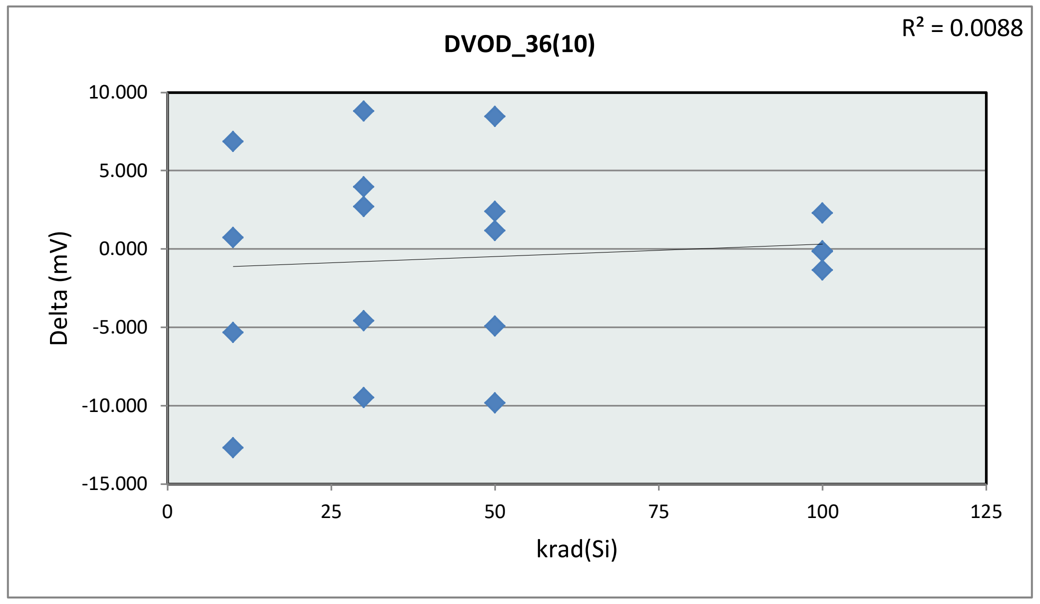
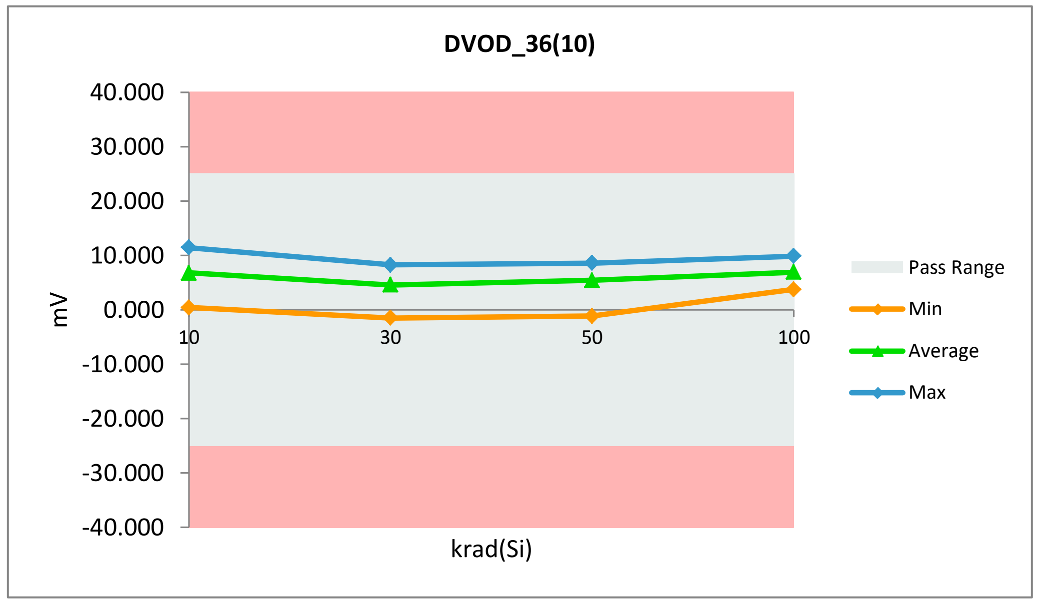
	DVOD_36(10)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	9.766	9.031	0.735
10	7	7.306	0.445	6.861
10	8	9.759	9.024	0.735
10	9	-1.213	4.120	-5.333
10	10	-1.216	11.484	-12.700
30	6	9.766	7.054	2.712
30	7	7.306	-1.479	8.785
30	8	9.759	5.809	3.950
30	9	-1.213	3.386	-4.599
30	10	-1.216	8.279	-9.495
50	6	9.766	8.611	1.155
50	7	7.306	-1.145	8.451
50	8	9.759	7.371	2.388
50	9	-1.213	3.718	-4.931
50	10	-1.216	8.611	-9.827
100	B011	3.627	3.771	-0.144
100	B012	6.102	6.252	-0.150
100	B013	7.293	4.994	2.299
100	B014	8.516	9.883	-1.367
100	B015	9.766	9.917	-0.151
	Max	9.766	11.484	8.785
	Average	5.425	5.957	-0.531
	Min	-1.216	-1.479	-12.700
	Std Dev	4.722	3.700	5.850



	DVOD_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.445	-1.479	-1.145	3.771
Average	6.821	4.610	5.433	6.963
Max	11.484	8.279	8.611	9.917
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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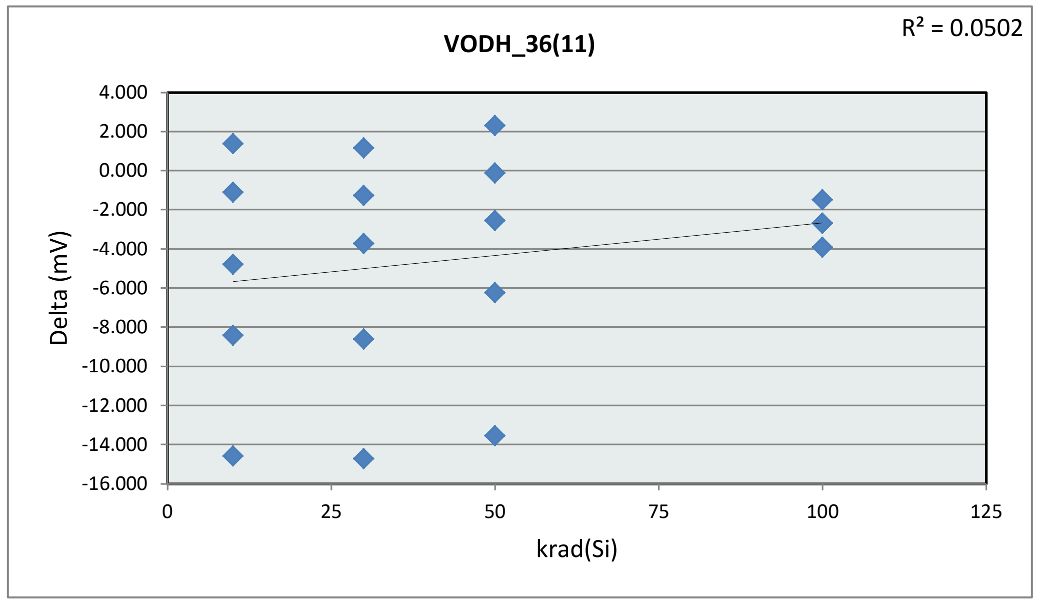
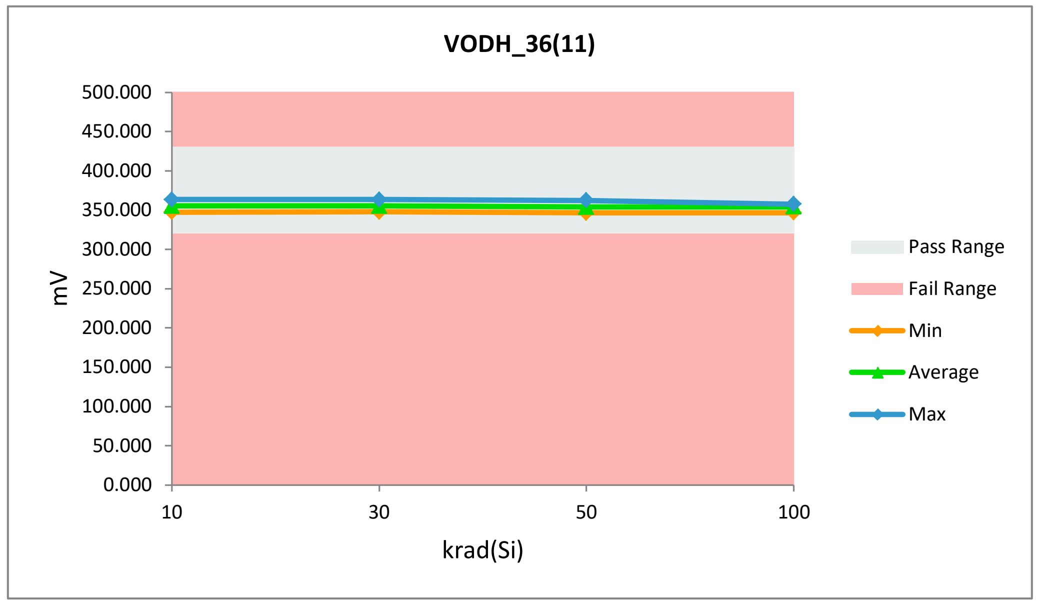
	VODH_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	430	430
Min Limit	320	320

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	343.903	352.331	-8.428
10	7	354.898	356.012	-1.114
10	8	348.791	363.375	-14.584
10	9	352.447	357.239	-4.792
10	10	348.783	347.422	1.361
30	6	343.903	352.513	-8.610
30	7	354.898	356.178	-1.280
30	8	348.791	363.510	-14.719
30	9	352.447	356.177	-3.730
30	10	348.783	347.632	1.151
50	6	343.903	350.131	-6.228
50	7	354.898	355.018	-0.120
50	8	348.791	362.349	-13.558
50	9	352.447	355.015	-2.568
50	10	348.783	346.474	2.309
100	B011	351.225	355.149	-3.924
100	B012	353.664	356.369	-2.705
100	B013	356.110	357.592	-1.482
100	B014	352.450	355.151	-2.701
100	B015	343.903	346.601	-2.698
	Max	356.110	363.510	2.309
	Average	350.191	354.612	-4.421
	Min	343.903	346.474	-14.719
	Std Dev	4.006	5.145	5.133



	VODH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	347.422	347.632	346.474	346.601
Average	355.276	355.202	353.797	354.172
Max	363.375	363.510	362.349	357.592
UL	430.000	430.000	430.000	430.000



LDR UnBiased TID Report
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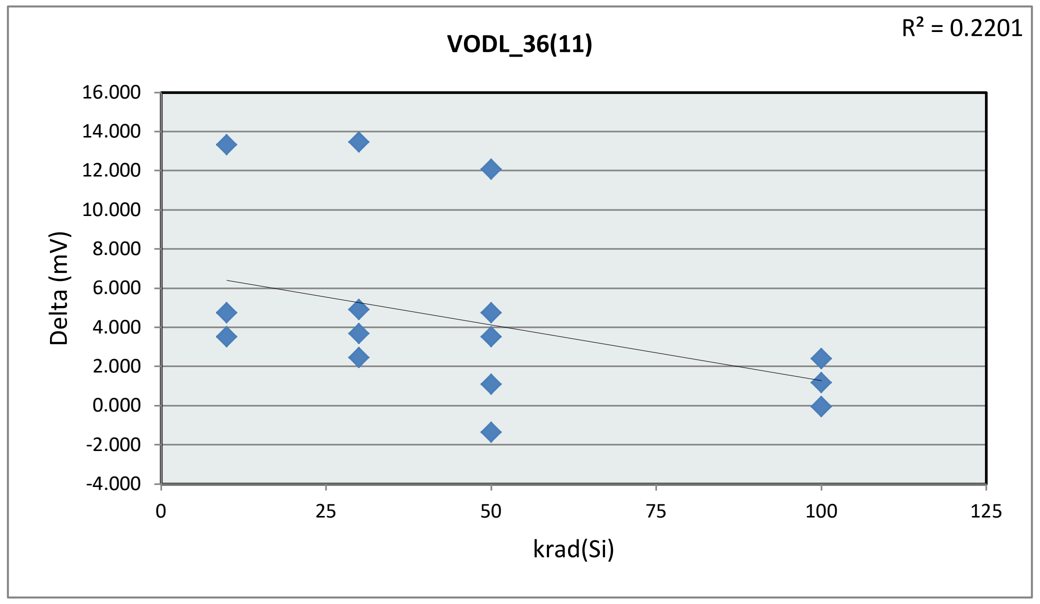
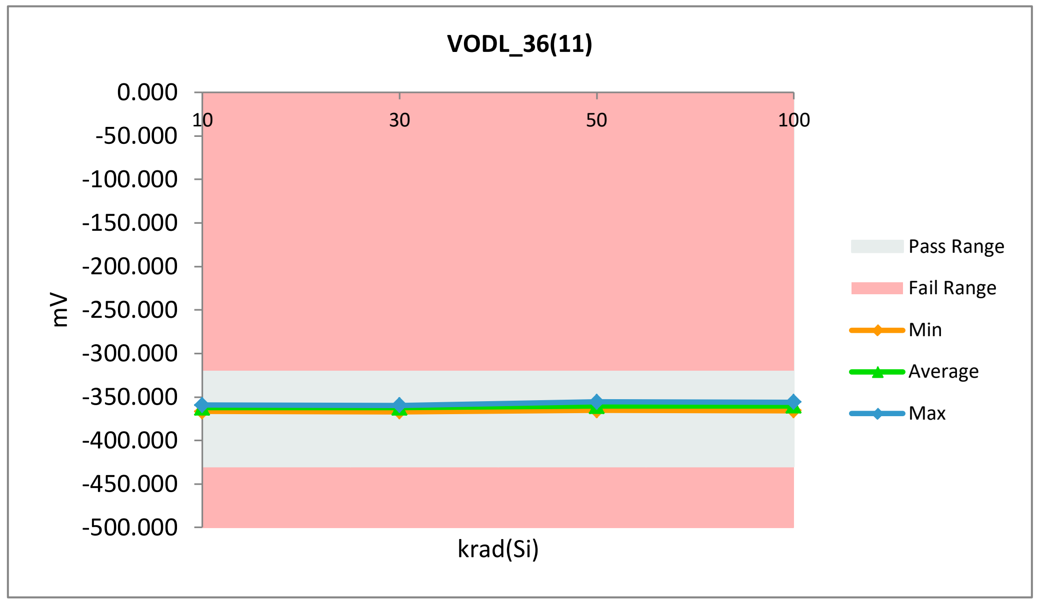
	VODL_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	-320	-320
Min Limit	-430	-430

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	-354.702	-359.428	4.726
10	7	-357.142	-361.882	4.740
10	8	-353.479	-366.791	13.312
10	9	-359.594	-363.109	3.515
10	10	-357.151	-360.655	3.504
30	6	-354.702	-359.610	4.908
30	7	-357.142	-362.052	4.910
30	8	-353.479	-366.935	13.456
30	9	-359.594	-363.275	3.681
30	10	-357.151	-359.605	2.454
50	6	-354.702	-358.227	3.525
50	7	-357.142	-361.890	4.748
50	8	-353.479	-365.551	12.072
50	9	-359.594	-360.671	1.077
50	10	-357.151	-355.779	-1.372
100	B011	-357.152	-359.544	2.392
100	B012	-357.154	-359.545	2.391
100	B013	-365.701	-365.652	-0.049
100	B014	-360.812	-360.764	-0.048
100	B015	-354.702	-355.875	1.173
	Max	-353.479	-355.779	13.456
	Average	-357.086	-361.342	4.256
	Min	-365.701	-366.935	-1.372
	Std Dev	2.980	3.188	4.166



	VODL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-366.791	-366.935	-365.551	-365.652
Average	-362.373	-362.295	-360.424	-360.276
Max	-359.428	-359.605	-355.779	-355.875
UL	-320.000	-320.000	-320.000	-320.000



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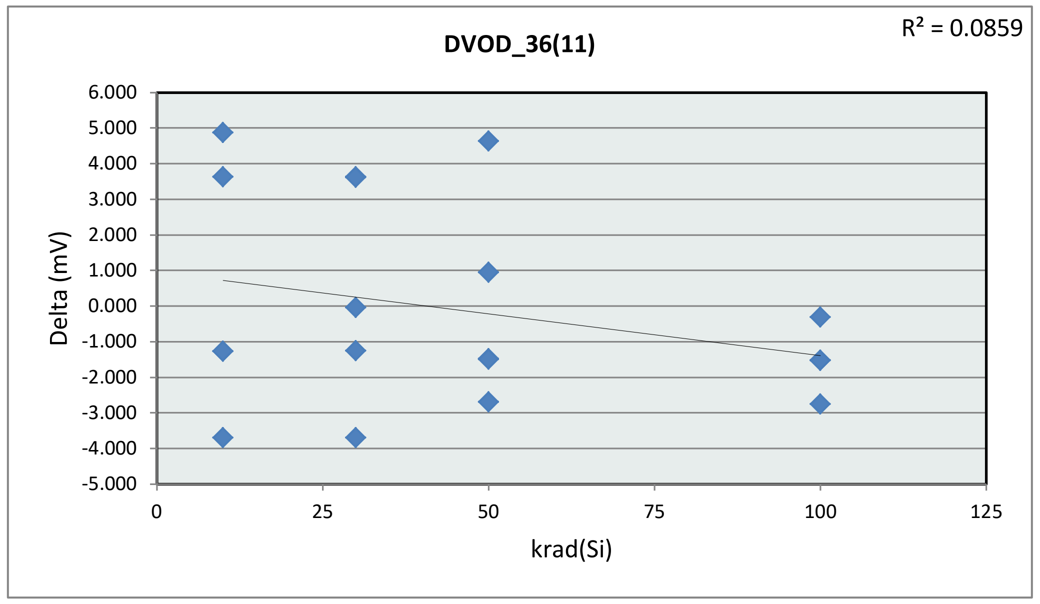
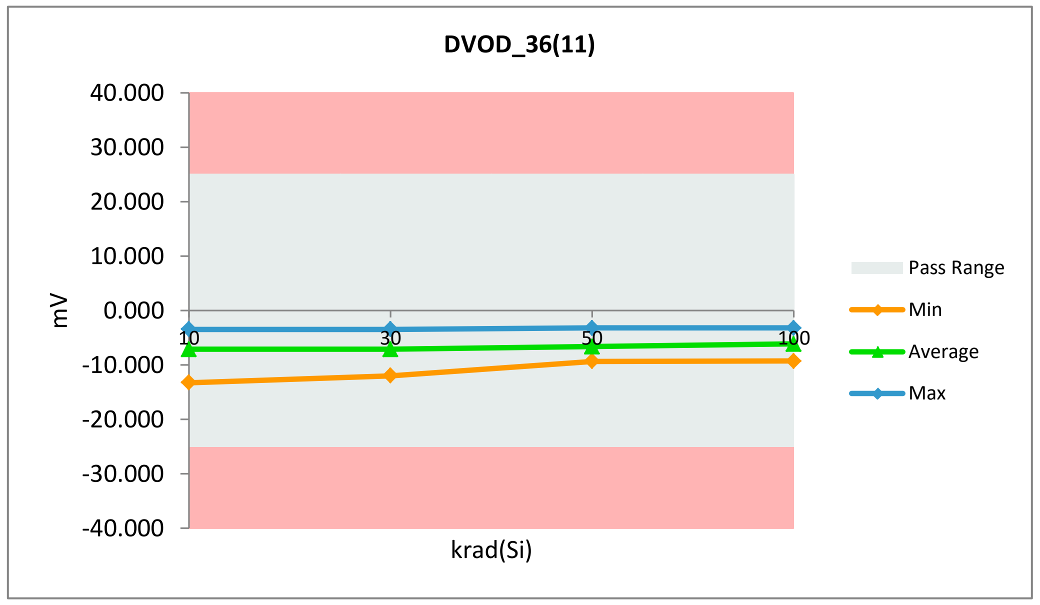
	DVOD_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.799	-7.097	-3.702
10	7	-2.244	-5.870	3.626
10	8	-4.688	-3.416	-1.272
10	9	-7.147	-5.870	-1.277
10	10	-8.368	-13.233	4.865
30	6	-10.799	-7.097	-3.702
30	7	-2.244	-5.874	3.630
30	8	-4.688	-3.425	-1.263
30	9	-7.147	-7.099	-0.048
30	10	-8.368	-11.973	3.605
50	6	-10.799	-8.096	-2.703
50	7	-2.244	-6.872	4.628
50	8	-4.688	-3.202	-1.486
50	9	-7.147	-5.656	-1.491
50	10	-8.368	-9.305	0.937
100	B011	-5.926	-4.395	-1.531
100	B012	-3.490	-3.176	-0.314
100	B013	-9.591	-8.059	-1.532
100	B014	-8.362	-5.613	-2.749
100	B015	-10.799	-9.274	-1.525
	Max	-2.244	-3.176	4.865
	Average	-6.895	-6.730	-0.165
	Min	-10.799	-13.233	-3.702
	Std Dev	2.984	2.753	2.747



	DVOD_36(11)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-13.233	-11.973	-9.305	-9.274
Average	-7.097	-7.094	-6.626	-6.103
Max	-3.416	-3.425	-3.202	-3.176
UL	25.000	25.000	25.000	25.000



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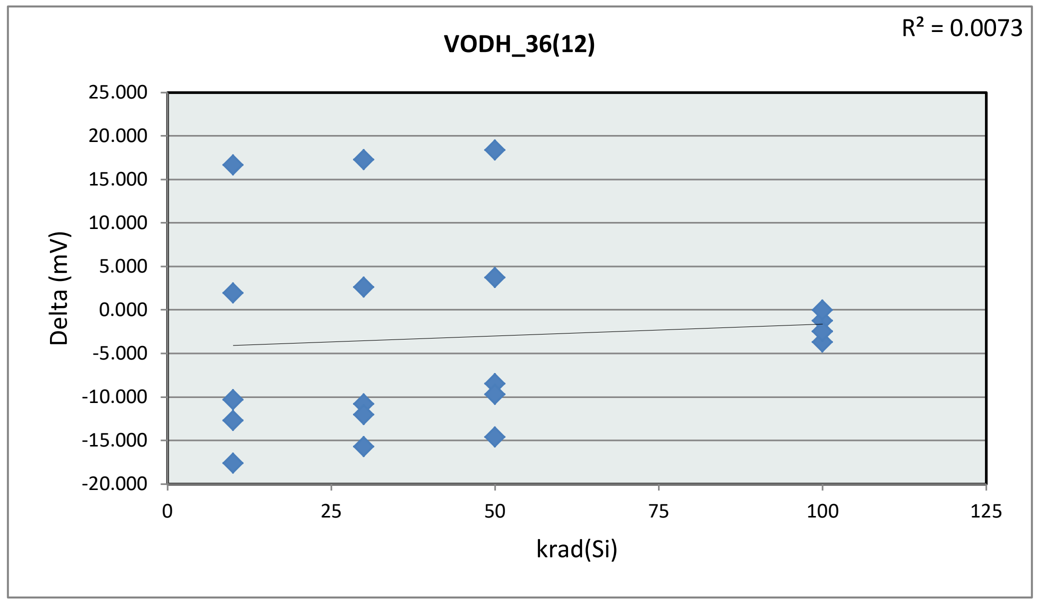
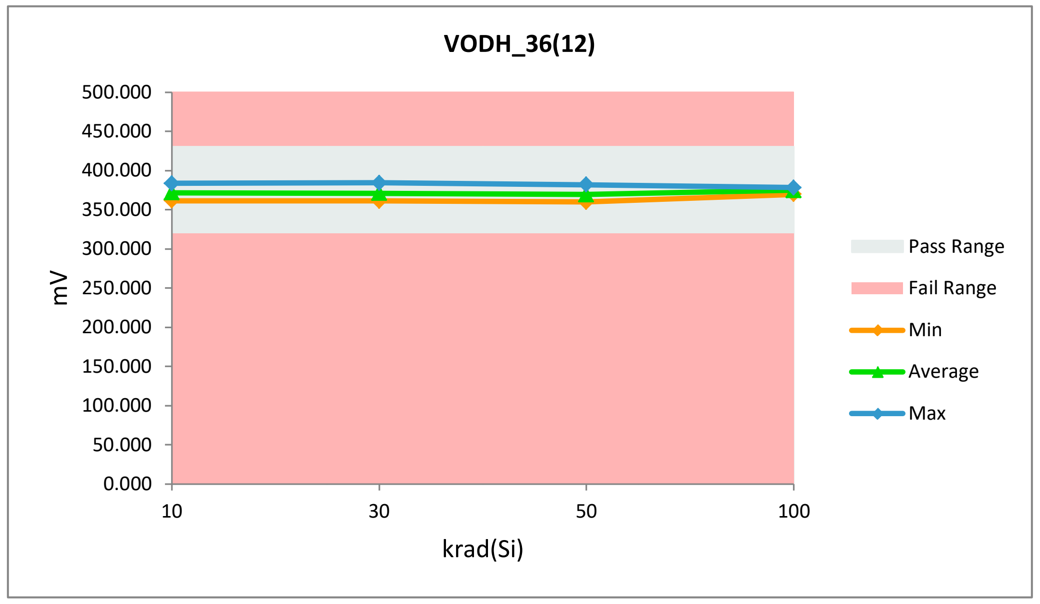
		VODH_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	430	430	
	Min Limit	320	320	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	370.929	368.982	1.947
10	7	378.256	361.621	16.635
10	8	373.370	383.705	-10.335
10	9	358.718	371.436	-12.718
10	10	355.049	372.663	-17.614
30	6	370.929	368.307	2.622
30	7	378.256	360.986	17.270
30	8	373.370	384.184	-10.814
30	9	358.718	370.749	-12.031
30	10	355.049	370.753	-15.704
50	6	370.929	367.205	3.724
50	7	378.256	359.882	18.374
50	8	373.370	381.859	-8.489
50	9	358.718	368.425	-9.707
50	10	355.049	369.649	-14.600
100	B011	372.138	374.609	-2.471
100	B012	366.042	369.740	-3.698
100	B013	377.027	378.278	-1.251
100	B014	378.250	378.276	-0.026
100	B015	370.929	373.406	-2.477
	Max	378.256	384.184	18.374
	Average	368.668	371.736	-3.068
	Min	355.049	359.882	-17.614
	Std Dev	8.574	6.950	10.865



	VODH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	430	mV		
Min Limit	320	mV		
krad(Si)	10	30	50	100
LL	320.000	320.000	320.000	320.000
Min	361.621	360.986	359.882	369.740
Average	371.681	370.996	369.404	374.862
Max	383.705	384.184	381.859	378.278
UL	430.000	430.000	430.000	430.000



LDR UnBiased TID Report
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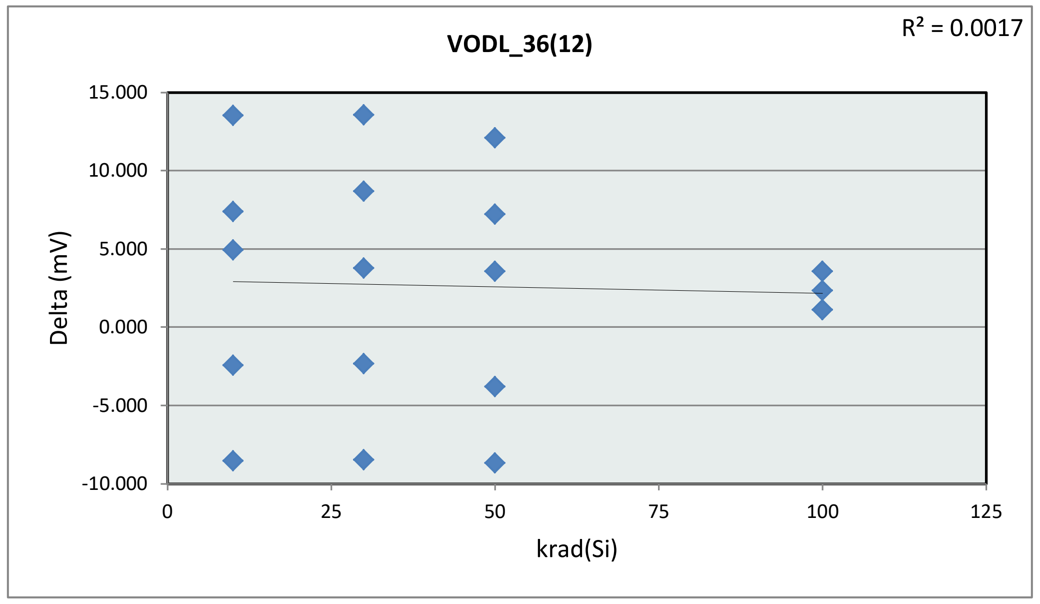
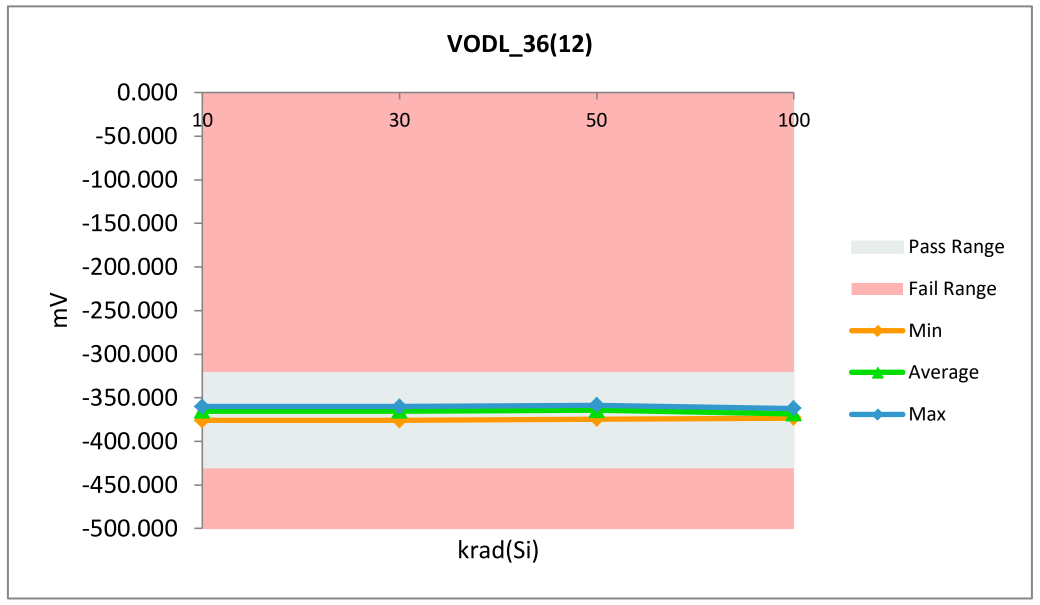
		VODL_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	-320	-320	
	Min Limit	-430	-430	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-362.395	-359.954	-2.441
10	7	-370.957	-362.407	-8.550
10	8	-362.399	-375.910	13.511
10	9	-358.718	-366.091	7.373
10	10	-357.498	-362.409	4.911
30	6	-362.395	-360.042	-2.353
30	7	-370.957	-362.477	-8.480
30	8	-362.399	-375.941	13.542
30	9	-358.718	-367.378	8.660
30	10	-357.498	-361.265	3.767
50	6	-362.395	-358.604	-3.791
50	7	-370.957	-362.262	-8.695
50	8	-362.399	-374.497	12.098
50	9	-358.718	-365.938	7.220
50	10	-357.498	-361.048	3.550
100	B011	-368.520	-372.072	3.552
100	B012	-358.727	-362.278	3.551
100	B013	-372.187	-373.293	1.106
100	B014	-368.520	-370.849	2.329
100	B015	-362.395	-363.500	1.105
	Max	-357.498	-358.604	13.542
	Average	-363.312	-365.911	2.598
	Min	-372.187	-375.941	-8.695
	Std Dev	5.130	5.761	6.841

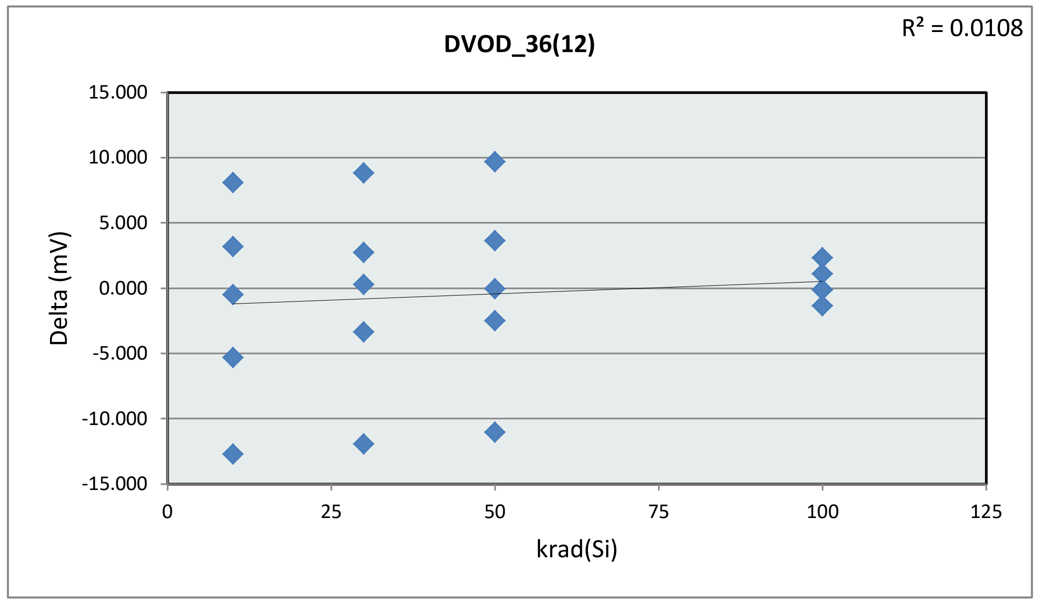


	VODL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	-320	mV		
Min Limit	-430	mV		
krad(Si)	10	30	50	100
LL	-430.000	-430.000	-430.000	-430.000
Min	-375.910	-375.941	-374.497	-373.293
Average	-365.354	-365.421	-364.470	-368.398
Max	-359.954	-360.042	-358.604	-362.278
UL	-320.000	-320.000	-320.000	-320.000

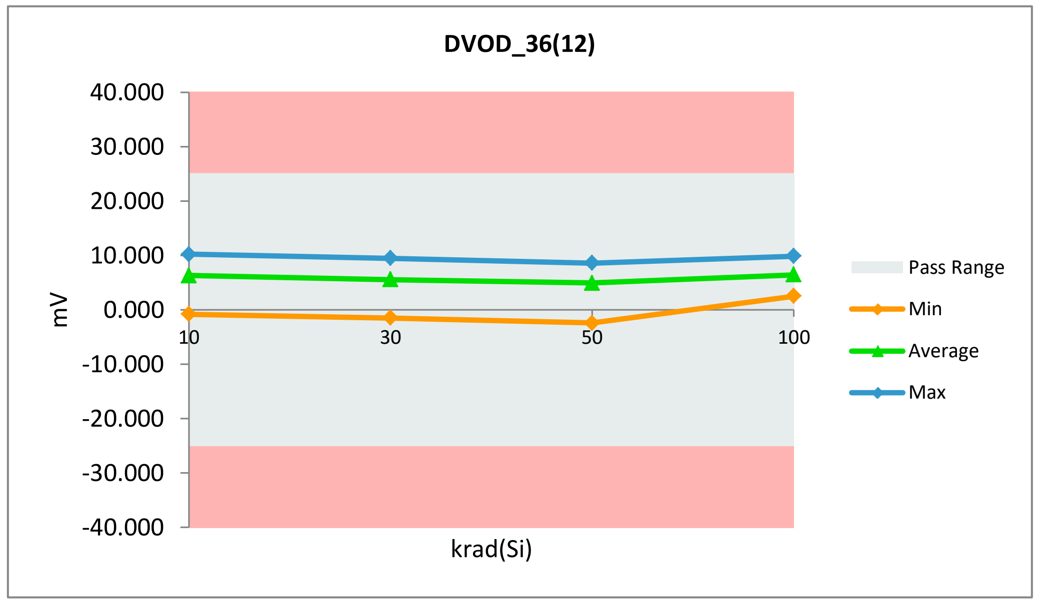


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVOD_36(12)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	8.534	9.028	-0.494
10	7	7.299	-0.786	8.085
10	8	10.971	7.795	3.176
10	9	-0.001	5.344	-5.345
10	10	-2.449	10.254	-12.703
30	6	8.534	8.264	0.270
30	7	7.299	-1.492	8.791
30	8	10.971	8.243	2.728
30	9	-0.001	3.371	-3.372
30	10	-2.449	9.488	-11.937
50	6	8.534	8.601	-0.067
50	7	7.299	-2.379	9.678
50	8	10.971	7.362	3.609
50	9	-0.001	2.486	-2.487
50	10	-2.449	8.601	-11.050
100	B011	3.618	2.538	1.080
100	B012	7.314	7.463	-0.149
100	B013	4.840	4.985	-0.145
100	B014	9.730	7.427	2.303
100	B015	8.534	9.906	-1.372
	Max	10.971	10.254	9.678
	Average	5.355	5.825	-0.470
	Min	-2.449	-2.379	-12.703
	Std Dev	4.820	3.921	6.254



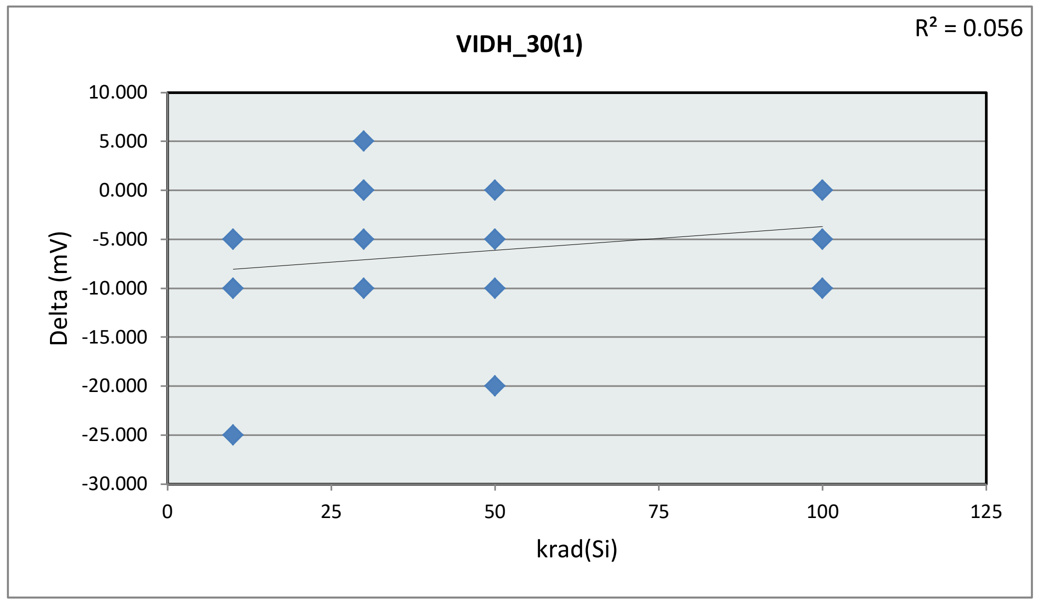
	DVOD_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.786	-1.492	-2.379	2.538
Average	6.327	5.575	4.934	6.464
Max	10.254	9.488	8.601	9.906
UL	25.000	25.000	25.000	25.000



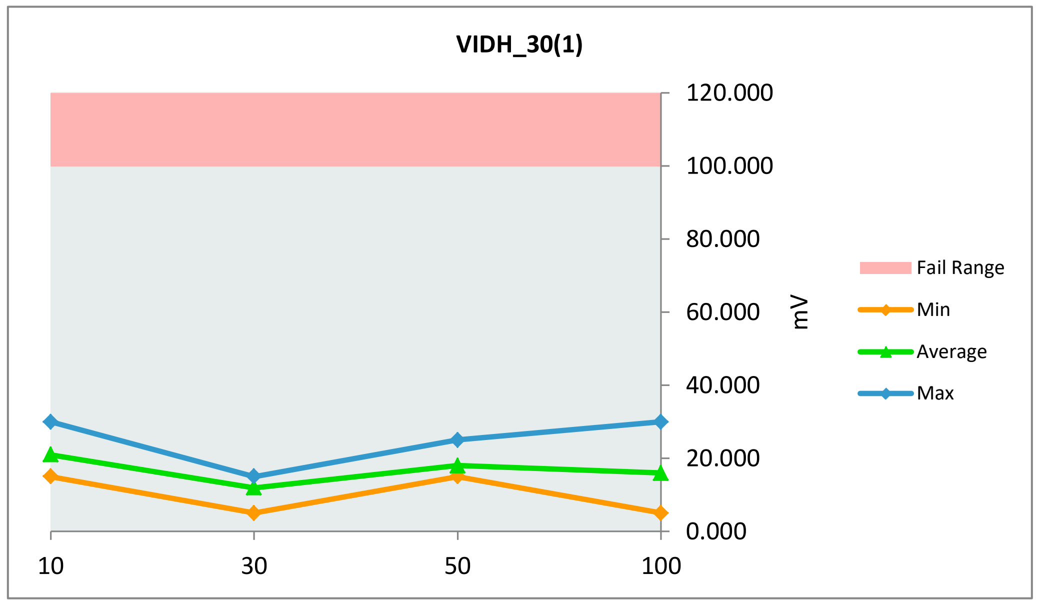
LDR UnBiased TID Report
SN55LVCP22A-SP

	VIDH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	30.000	-25.000
10	7	10.000	20.000	-10.000
10	8	10.000	15.000	-5.000
10	9	15.000	20.000	-5.000
10	10	10.000	20.000	-10.000
30	6	5.000	15.000	-10.000
30	7	10.000	15.000	-5.000
30	8	10.000	5.000	5.000
30	9	15.000	15.000	0.000
30	10	10.000	10.000	0.000
50	6	5.000	25.000	-20.000
50	7	10.000	20.000	-10.000
50	8	10.000	15.000	-5.000
50	9	15.000	15.000	0.000
50	10	10.000	15.000	-5.000
100	B011	15.000	25.000	-10.000
100	B012	25.000	30.000	-5.000
100	B013	10.000	10.000	0.000
100	B014	5.000	5.000	0.000
100	B015	5.000	10.000	-5.000
	Max	25.000	30.000	5.000
	Average	10.500	16.750	-6.250
	Min	5.000	5.000	-25.000
	Std Dev	4.840	7.122	7.048

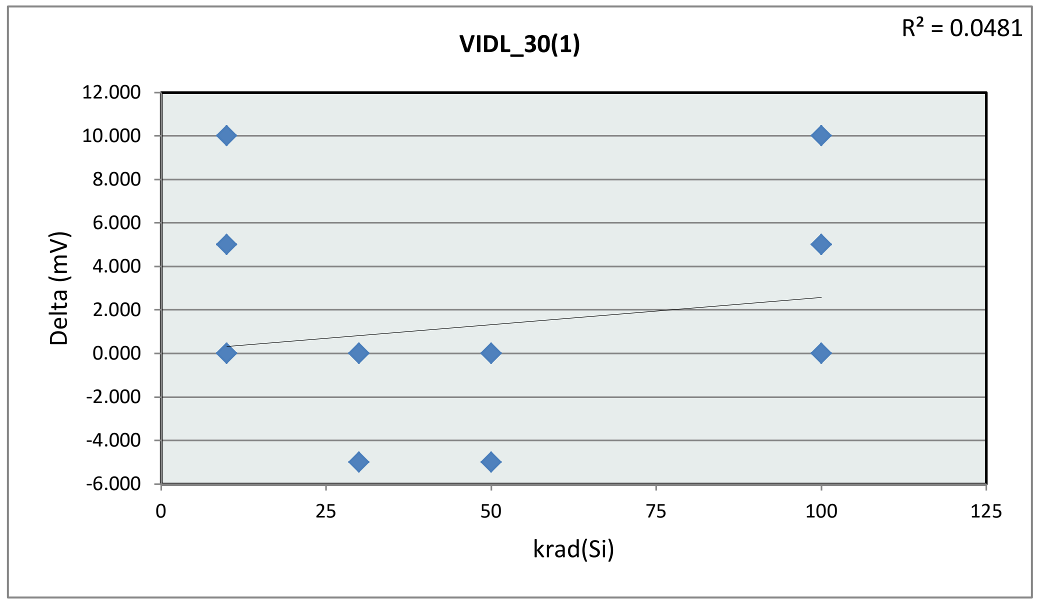


	VIDH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	5.000	15.000	5.000
Average	21.000	12.000	18.000	16.000
Max	30.000	15.000	25.000	30.000
UL	100.000	100.000	100.000	100.000

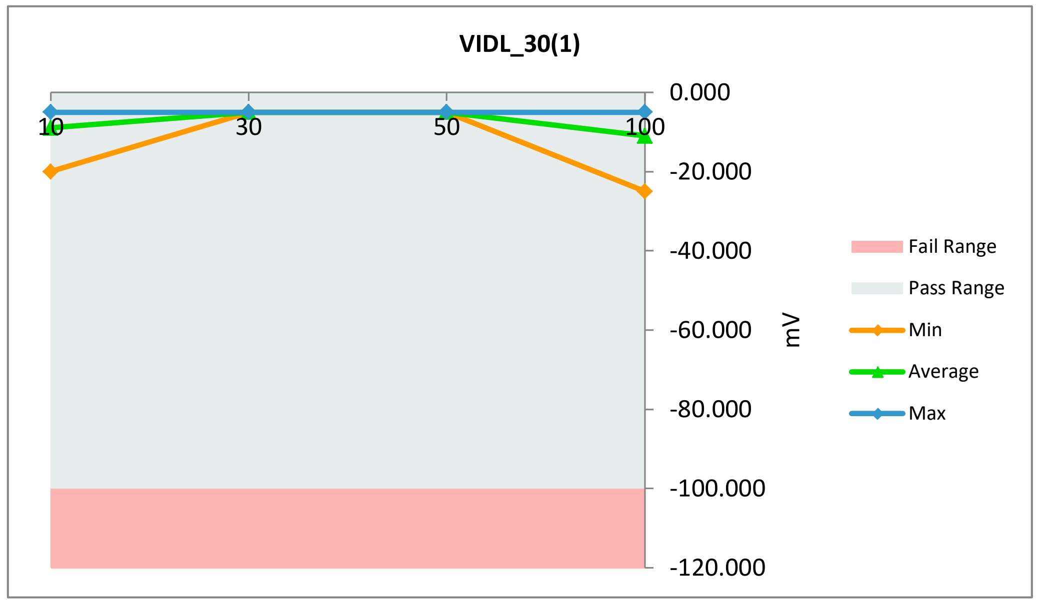


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_30(1)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-5.000	-10.000	5.000
10	7	-5.000	-5.000	0.000
10	8	-10.000	-20.000	10.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-5.000	-5.000	0.000
30	8	-10.000	-5.000	-5.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-5.000	-5.000	0.000
50	7	-5.000	-5.000	0.000
50	8	-10.000	-5.000	-5.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-10.000	5.000
100	B014	-15.000	-25.000	10.000
100	B015	-5.000	-10.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-6.250	-7.500	1.250
	Min	-15.000	-25.000	-5.000
	Std Dev	2.751	5.501	3.932



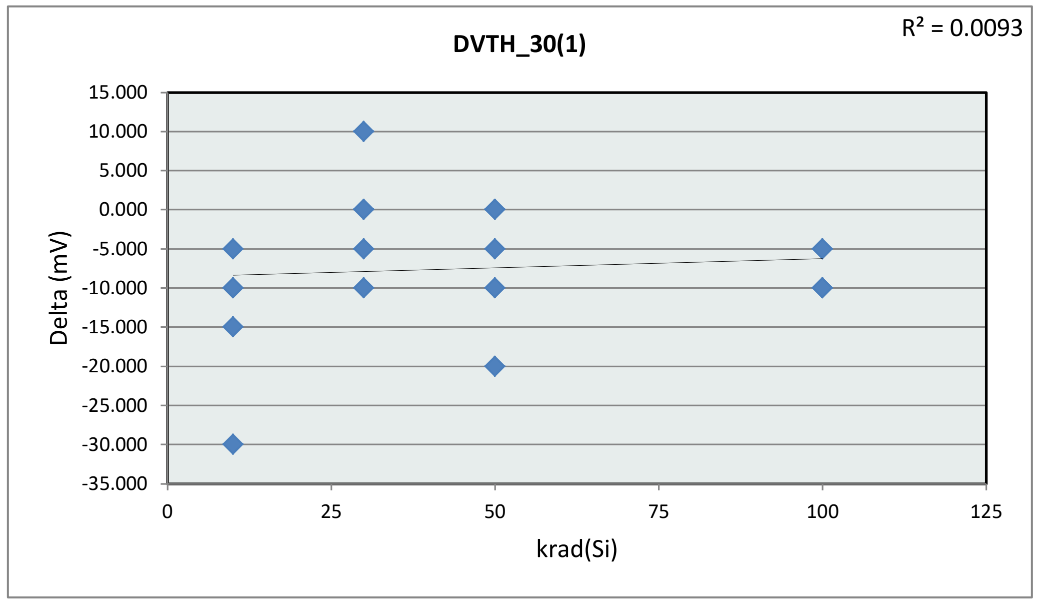
	VIDL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-20.000	-5.000	-5.000	-25.000
Average	-9.000	-5.000	-5.000	-11.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



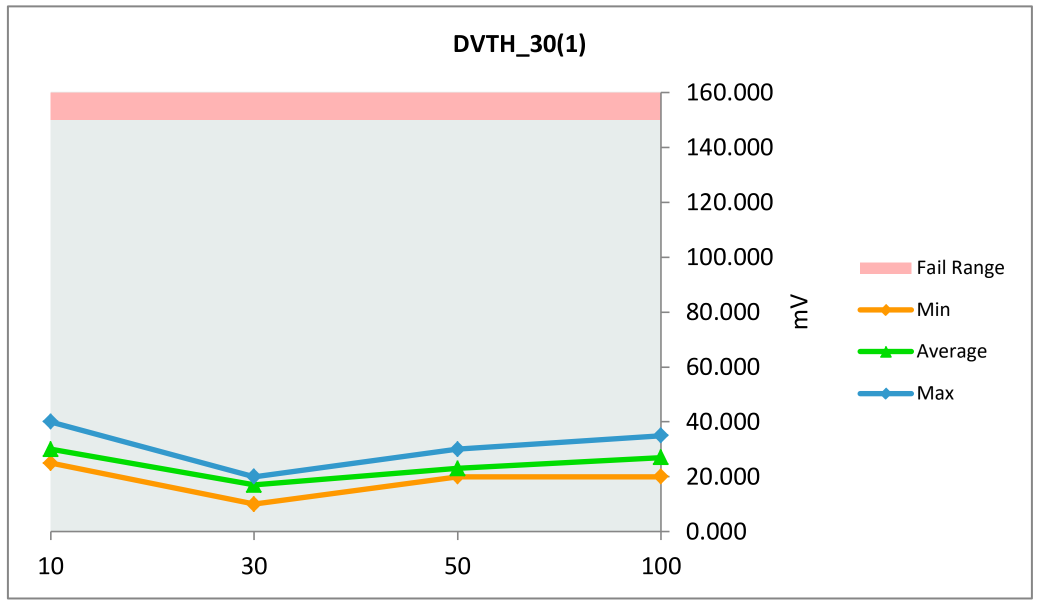
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	10.000	40.000	-30.000
10	7	15.000	25.000	-10.000
10	8	20.000	35.000	-15.000
10	9	20.000	25.000	-5.000
10	10	15.000	25.000	-10.000
30	6	10.000	20.000	-10.000
30	7	15.000	20.000	-5.000
30	8	20.000	10.000	10.000
30	9	20.000	20.000	0.000
30	10	15.000	15.000	0.000
50	6	10.000	30.000	-20.000
50	7	15.000	25.000	-10.000
50	8	20.000	20.000	0.000
50	9	20.000	20.000	0.000
50	10	15.000	20.000	-5.000
100	B011	20.000	30.000	-10.000
100	B012	30.000	35.000	-5.000
100	B013	15.000	20.000	-5.000
100	B014	20.000	30.000	-10.000
100	B015	10.000	20.000	-10.000
	Max	30.000	40.000	10.000
	Average	16.750	24.250	-7.500
	Min	10.000	10.000	-30.000
	Std Dev	4.940	7.304	8.351



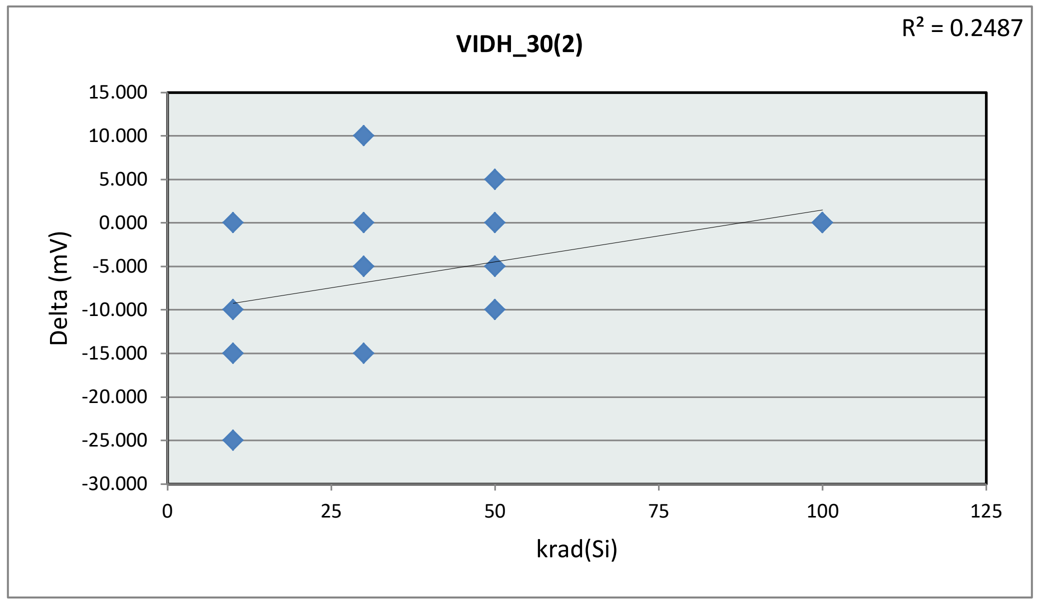
	DVTH_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	25.000	10.000	20.000	20.000
Average	30.000	17.000	23.000	27.000
Max	40.000	20.000	30.000	35.000
UL	150.000	150.000	150.000	150.000



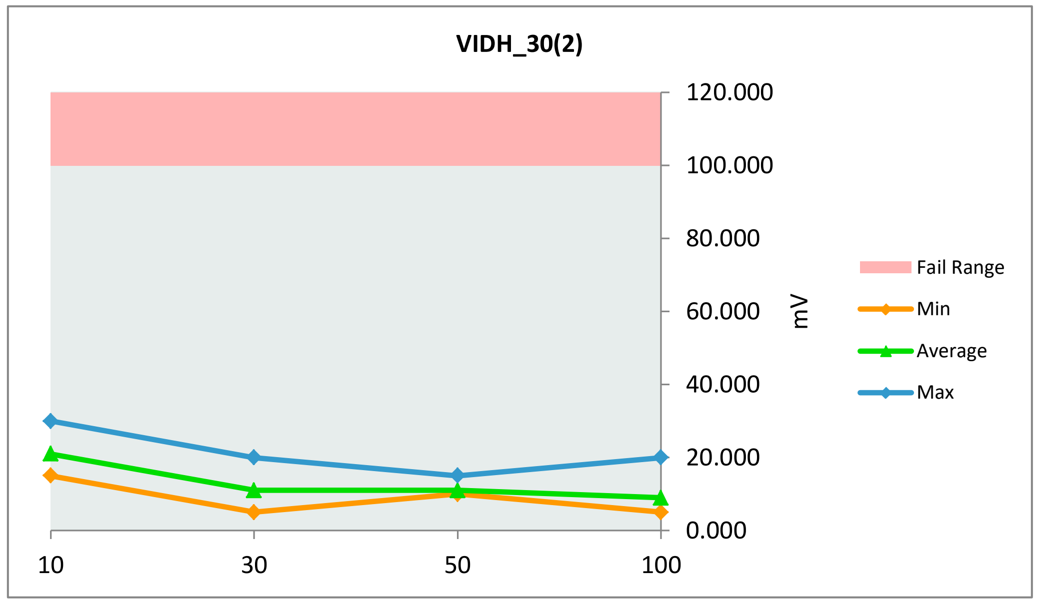
LDR UnBiased TID Report
SN55LVCP22A-SP

	VIDH_30(2)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	30.000	-25.000
10	7	15.000	15.000	0.000
10	8	5.000	15.000	-10.000
10	9	5.000	20.000	-15.000
10	10	10.000	25.000	-15.000
30	6	5.000	20.000	-15.000
30	7	15.000	5.000	10.000
30	8	5.000	10.000	-5.000
30	9	5.000	10.000	-5.000
30	10	10.000	10.000	0.000
50	6	5.000	15.000	-10.000
50	7	15.000	10.000	5.000
50	8	5.000	10.000	-5.000
50	9	5.000	10.000	-5.000
50	10	10.000	10.000	0.000
100	B011	20.000	20.000	0.000
100	B012	10.000	10.000	0.000
100	B013	5.000	5.000	0.000
100	B014	5.000	5.000	0.000
100	B015	5.000	5.000	0.000
	Max	20.000	30.000	10.000
	Average	8.250	13.000	-4.750
	Min	5.000	5.000	-25.000
	Std Dev	4.667	6.959	8.188

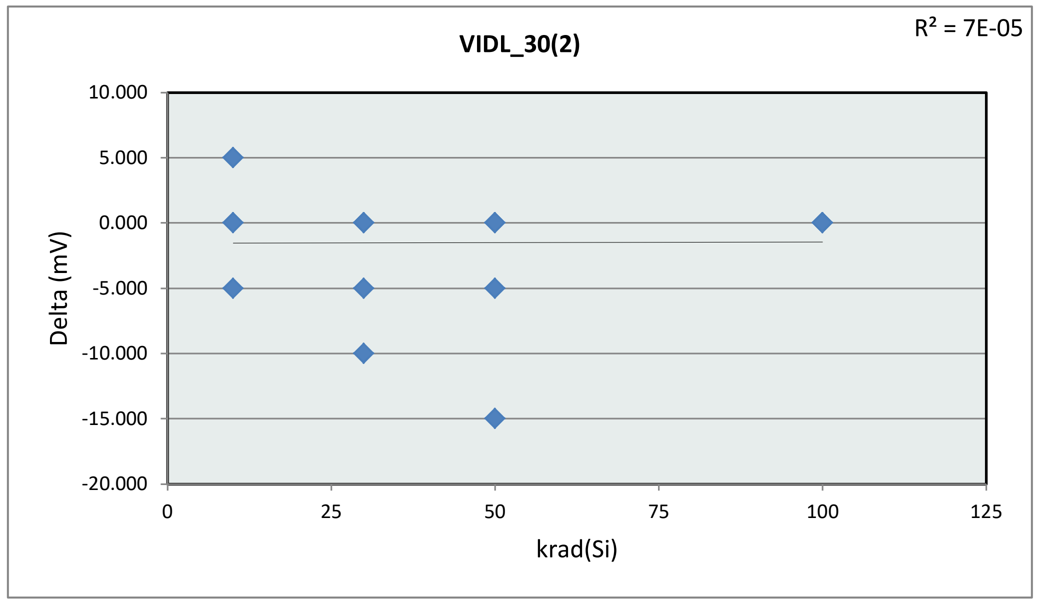


	VIDH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	5.000	10.000	5.000
Average	21.000	11.000	11.000	9.000
Max	30.000	20.000	15.000	20.000
UL	100.000	100.000	100.000	100.000

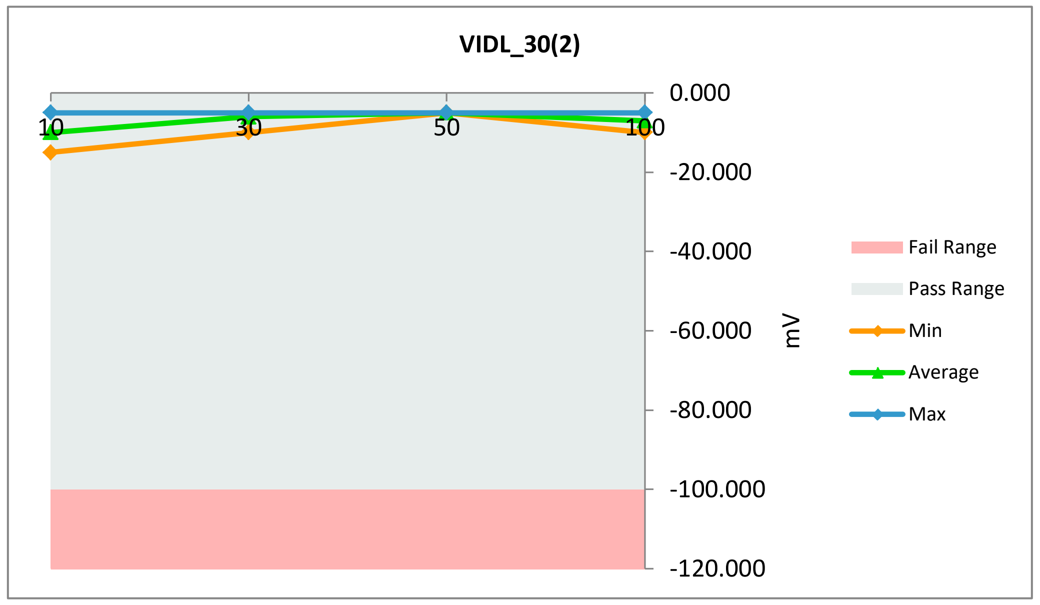


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.000	-10.000	0.000
10	7	-5.000	-10.000	5.000
10	8	-20.000	-15.000	-5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-10.000	5.000
30	6	-10.000	-5.000	-5.000
30	7	-5.000	-5.000	0.000
30	8	-20.000	-10.000	-10.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-10.000	-5.000	-5.000
50	7	-5.000	-5.000	0.000
50	8	-20.000	-5.000	-15.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-5.000	0.000
100	B014	-10.000	-10.000	0.000
100	B015	-10.000	-10.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-8.500	-7.000	-1.500
	Min	-20.000	-15.000	-15.000
	Std Dev	5.405	2.991	4.617

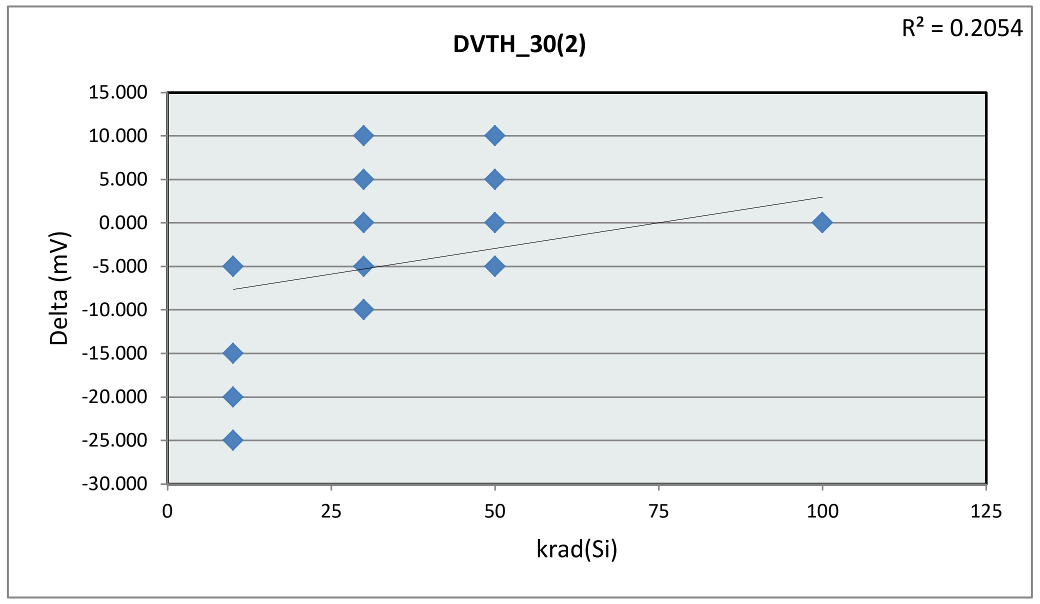


	VIDL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-10.000	-5.000	-10.000
Average	-10.000	-6.000	-5.000	-7.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

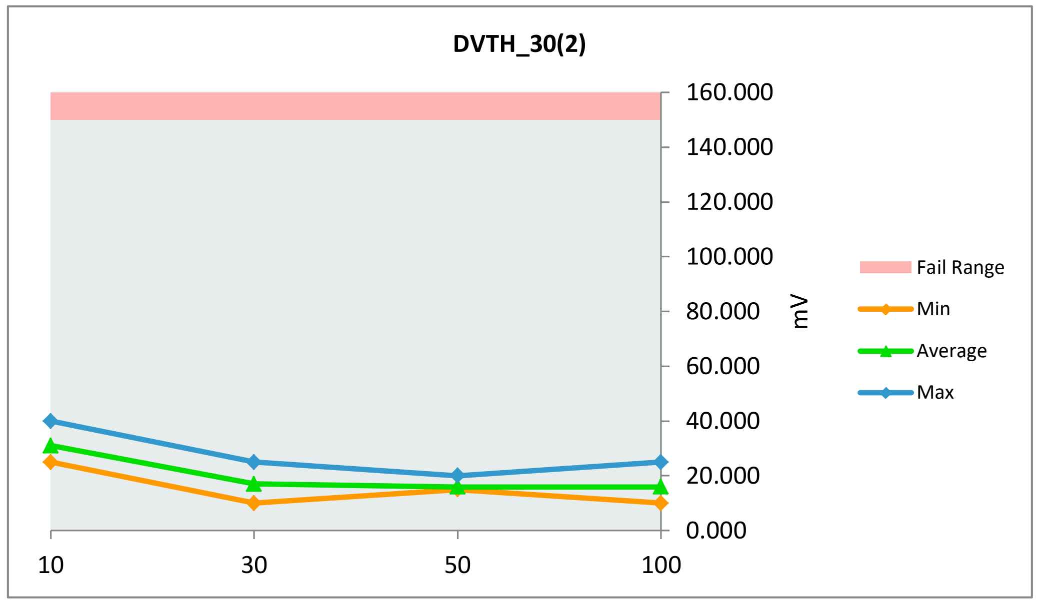


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	15.000	40.000	-25.000
10	7	20.000	25.000	-5.000
10	8	25.000	30.000	-5.000
10	9	10.000	25.000	-15.000
10	10	15.000	35.000	-20.000
30	6	15.000	25.000	-10.000
30	7	20.000	10.000	10.000
30	8	25.000	20.000	5.000
30	9	10.000	15.000	-5.000
30	10	15.000	15.000	0.000
50	6	15.000	20.000	-5.000
50	7	20.000	15.000	5.000
50	8	25.000	15.000	10.000
50	9	10.000	15.000	-5.000
50	10	15.000	15.000	0.000
100	B011	25.000	25.000	0.000
100	B012	15.000	15.000	0.000
100	B013	10.000	10.000	0.000
100	B014	15.000	15.000	0.000
100	B015	15.000	15.000	0.000
	Max	25.000	40.000	10.000
	Average	16.750	20.000	-3.250
	Min	10.000	10.000	-25.000
	Std Dev	5.200	8.111	8.926

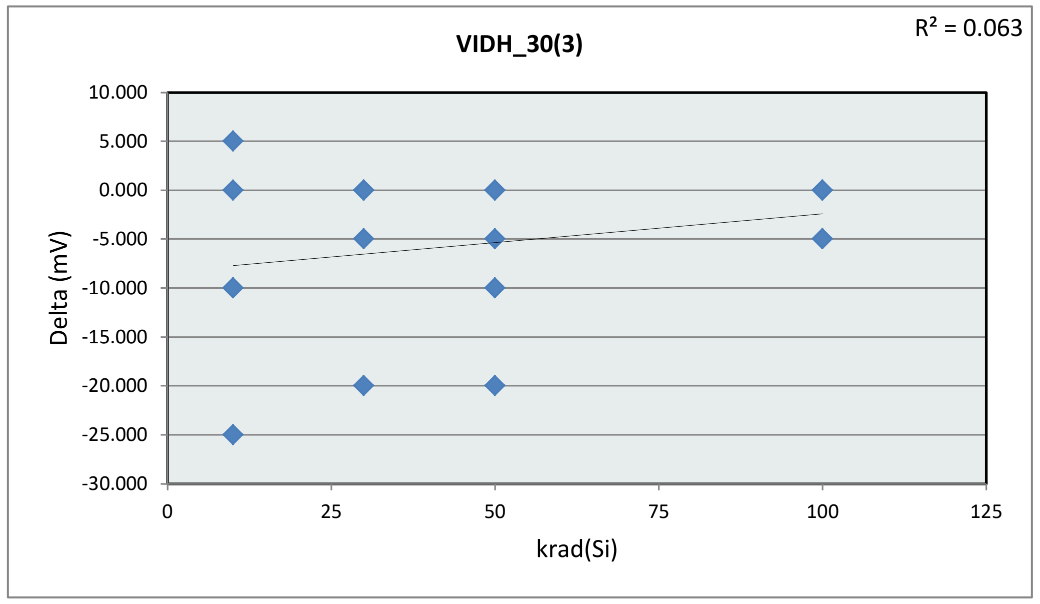


	DVTH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	25.000	10.000	15.000	10.000
Average	31.000	17.000	16.000	16.000
Max	40.000	25.000	20.000	25.000
UL	150.000	150.000	150.000	150.000

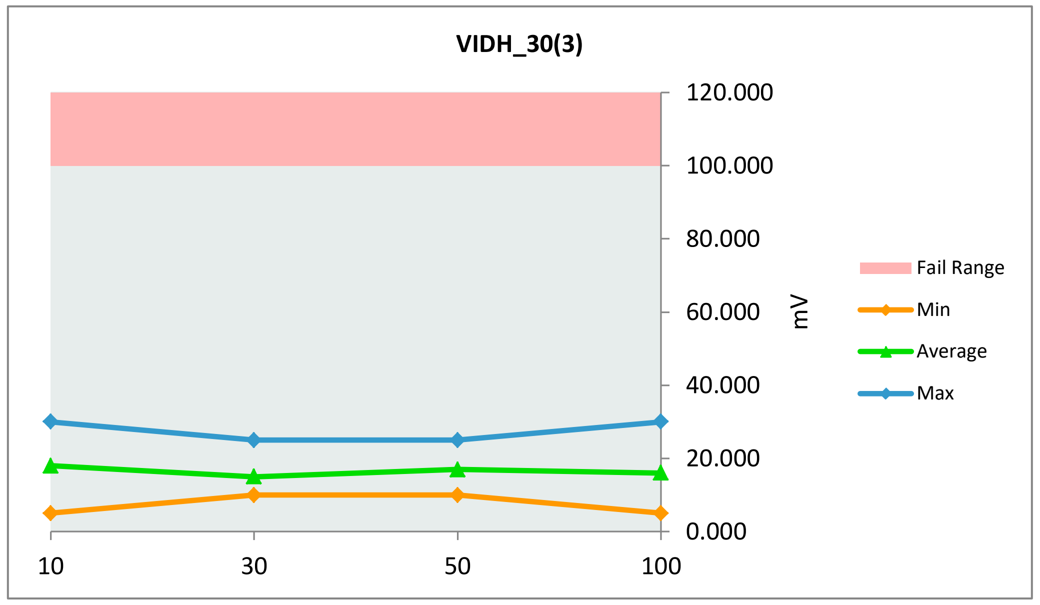


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	30.000	-25.000
10	7	10.000	20.000	-10.000
10	8	10.000	5.000	5.000
10	9	15.000	15.000	0.000
10	10	10.000	20.000	-10.000
30	6	5.000	25.000	-20.000
30	7	10.000	15.000	-5.000
30	8	10.000	10.000	0.000
30	9	15.000	15.000	0.000
30	10	10.000	10.000	0.000
50	6	5.000	25.000	-20.000
50	7	10.000	20.000	-10.000
50	8	10.000	10.000	0.000
50	9	15.000	15.000	0.000
50	10	10.000	15.000	-5.000
100	B011	25.000	25.000	0.000
100	B012	25.000	30.000	-5.000
100	B013	10.000	10.000	0.000
100	B014	5.000	5.000	0.000
100	B015	5.000	10.000	-5.000
	Max	25.000	30.000	5.000
	Average	11.000	16.500	-5.500
	Min	5.000	5.000	-25.000
	Std Dev	5.758	7.626	8.095

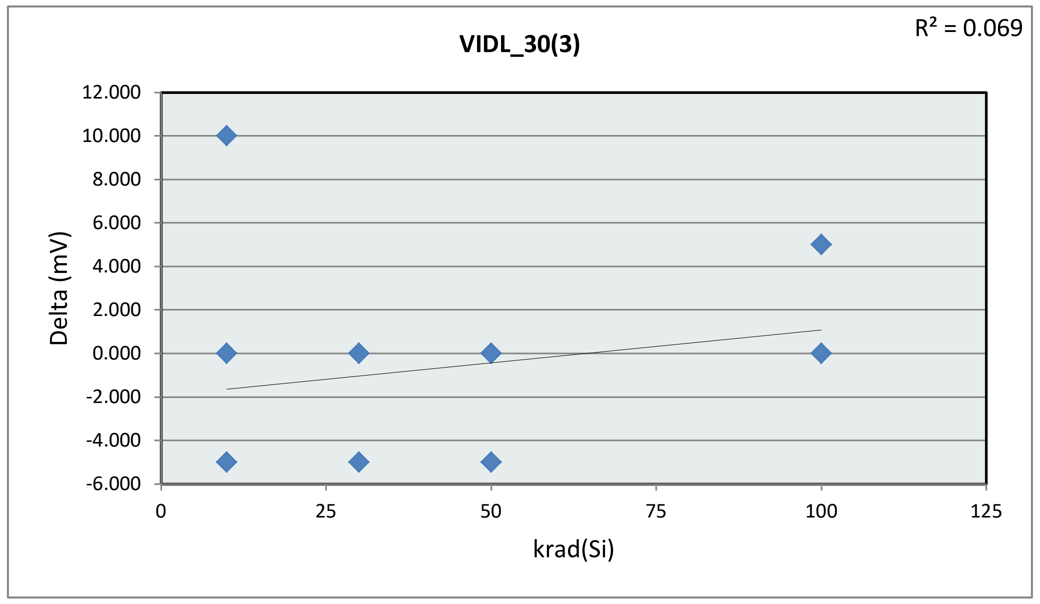


	VIDH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	10.000	10.000	5.000
Average	18.000	15.000	17.000	16.000
Max	30.000	25.000	25.000	30.000
UL	100.000	100.000	100.000	100.000

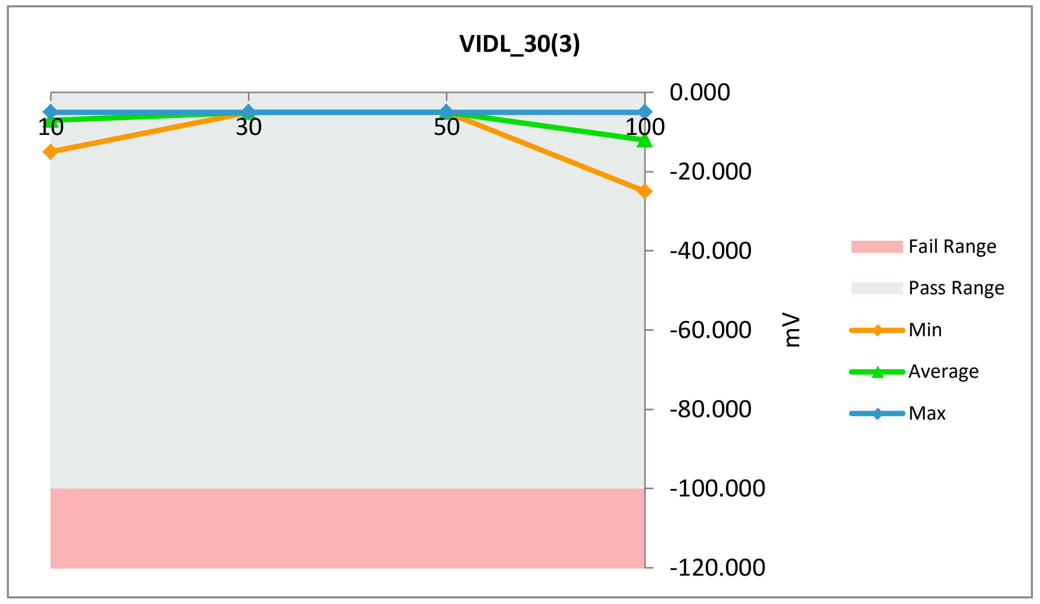


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-10.000	-5.000	-5.000
10	8	-5.000	-15.000	10.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-10.000	-5.000	-5.000
30	7	-10.000	-5.000	-5.000
30	8	-5.000	-5.000	0.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-10.000	-5.000	-5.000
50	7	-10.000	-5.000	-5.000
50	8	-5.000	-5.000	0.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-10.000	-10.000	0.000
100	B014	-20.000	-25.000	5.000
100	B015	-10.000	-15.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-7.750	-7.250	-0.500
	Min	-20.000	-25.000	-5.000
	Std Dev	3.796	5.250	3.940

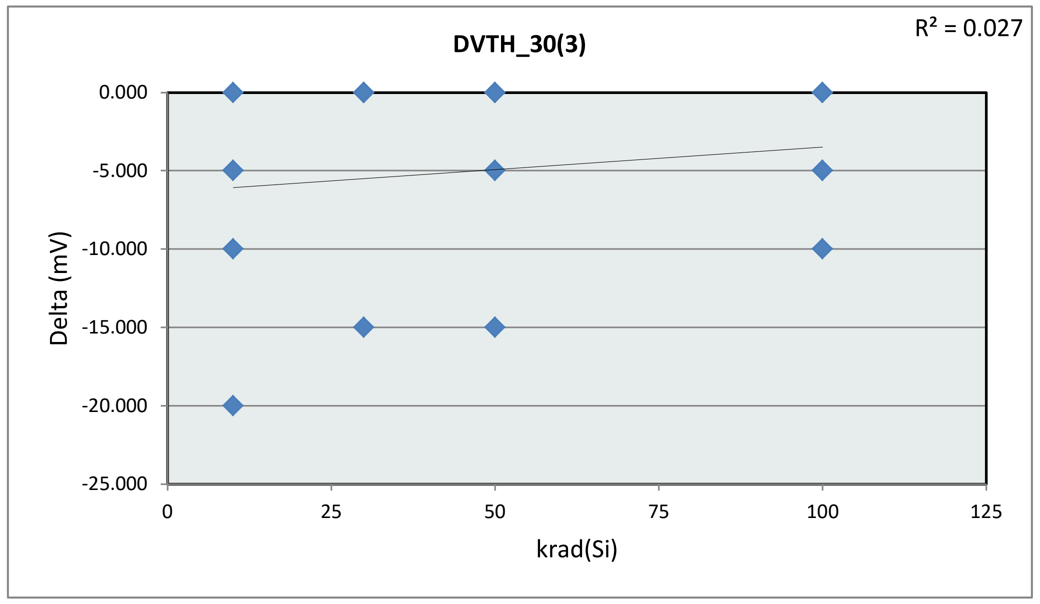


	VIDL_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-5.000	-5.000	-25.000
Average	-7.000	-5.000	-5.000	-12.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

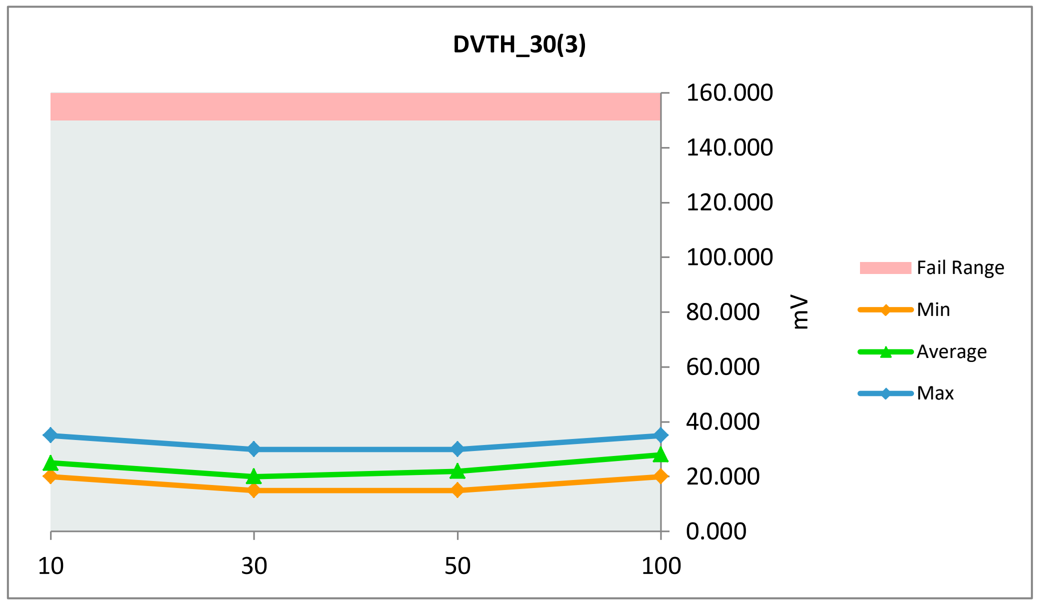


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_30(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	15.000	35.000	-20.000
10	7	20.000	25.000	-5.000
10	8	15.000	20.000	-5.000
10	9	20.000	20.000	0.000
10	10	15.000	25.000	-10.000
30	6	15.000	30.000	-15.000
30	7	20.000	20.000	0.000
30	8	15.000	15.000	0.000
30	9	20.000	20.000	0.000
30	10	15.000	15.000	0.000
50	6	15.000	30.000	-15.000
50	7	20.000	25.000	-5.000
50	8	15.000	15.000	0.000
50	9	20.000	20.000	0.000
50	10	15.000	20.000	-5.000
100	B011	30.000	30.000	0.000
100	B012	30.000	35.000	-5.000
100	B013	20.000	20.000	0.000
100	B014	25.000	30.000	-5.000
100	B015	15.000	25.000	-10.000
	Max	30.000	35.000	0.000
	Average	18.750	23.750	-5.000
	Min	15.000	15.000	-20.000
	Std Dev	4.833	6.257	6.070

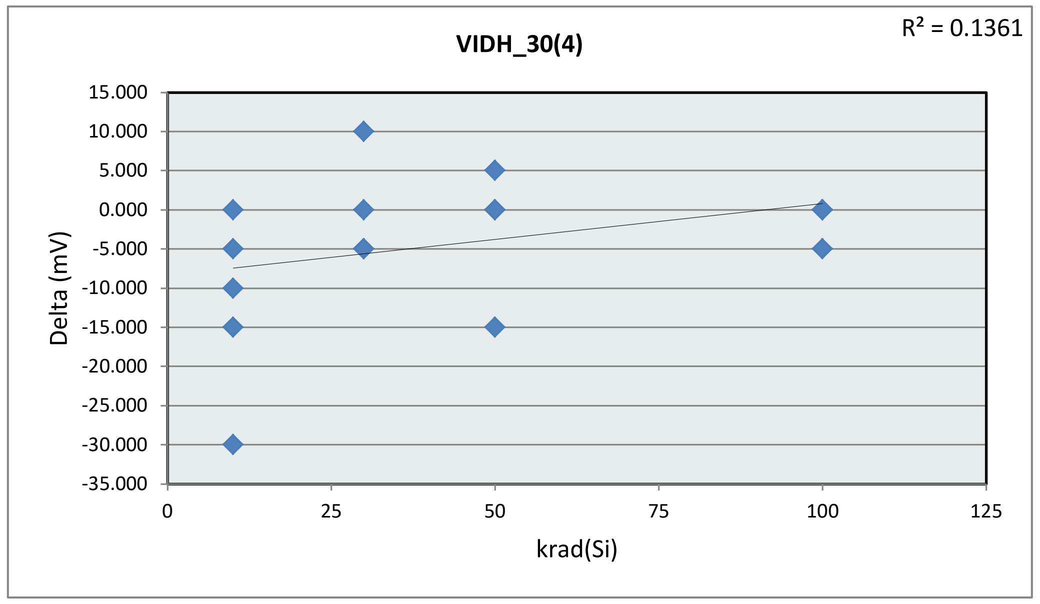


	DVTH_30(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	15.000	15.000	20.000
Average	25.000	20.000	22.000	28.000
Max	35.000	30.000	30.000	35.000
UL	150.000	150.000	150.000	150.000

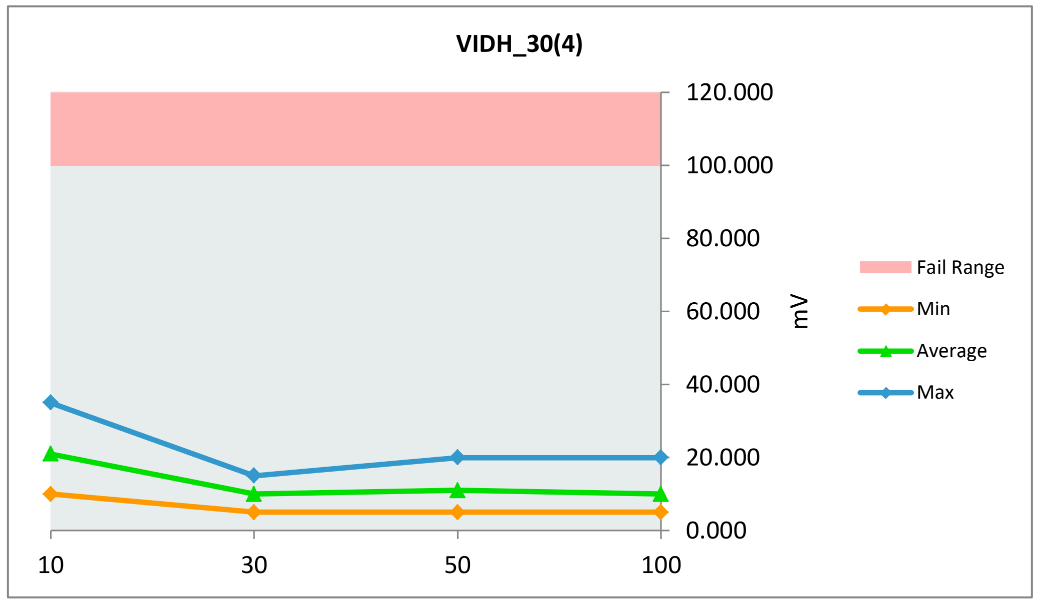


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_30(4)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	35.000	-30.000
10	7	15.000	15.000	0.000
10	8	5.000	10.000	-5.000
10	9	10.000	20.000	-10.000
10	10	10.000	25.000	-15.000
30	6	5.000	10.000	-5.000
30	7	15.000	5.000	10.000
30	8	5.000	5.000	0.000
30	9	10.000	15.000	-5.000
30	10	10.000	15.000	-5.000
50	6	5.000	20.000	-15.000
50	7	15.000	10.000	5.000
50	8	5.000	5.000	0.000
50	9	10.000	10.000	0.000
50	10	10.000	10.000	0.000
100	B011	20.000	20.000	0.000
100	B012	10.000	10.000	0.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	5.000	0.000
	Max	20.000	35.000	10.000
	Average	9.000	13.000	-4.000
	Min	5.000	5.000	-30.000
	Std Dev	4.472	7.847	8.522

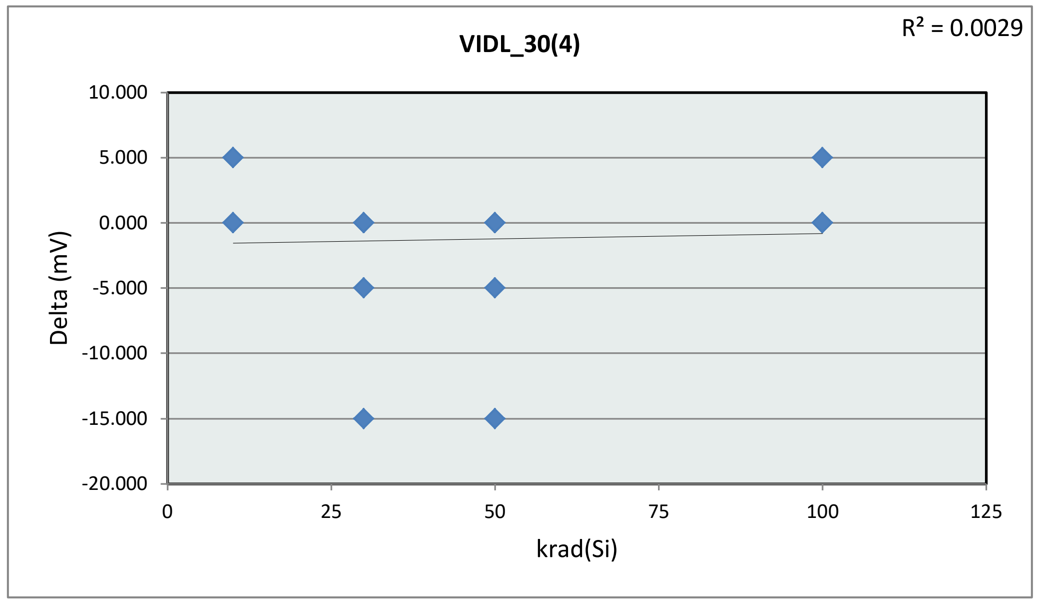


	VIDH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	5.000	5.000	5.000
Average	21.000	10.000	11.000	10.000
Max	35.000	15.000	20.000	20.000
UL	100.000	100.000	100.000	100.000

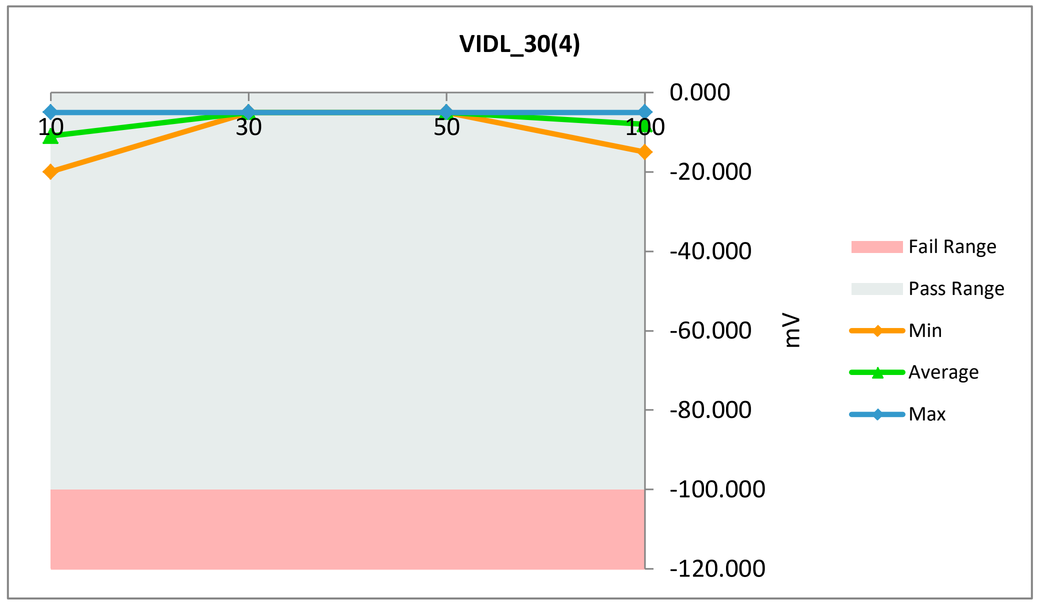


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.000	-10.000	0.000
10	7	-5.000	-10.000	5.000
10	8	-20.000	-20.000	0.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-10.000	5.000
30	6	-10.000	-5.000	-5.000
30	7	-5.000	-5.000	0.000
30	8	-20.000	-5.000	-15.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-10.000	-5.000	-5.000
50	7	-5.000	-5.000	0.000
50	8	-20.000	-5.000	-15.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-5.000	0.000
100	B014	-10.000	-15.000	5.000
100	B015	-10.000	-10.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-8.500	-7.250	-1.250
	Min	-20.000	-20.000	-15.000
	Std Dev	5.405	4.128	5.350

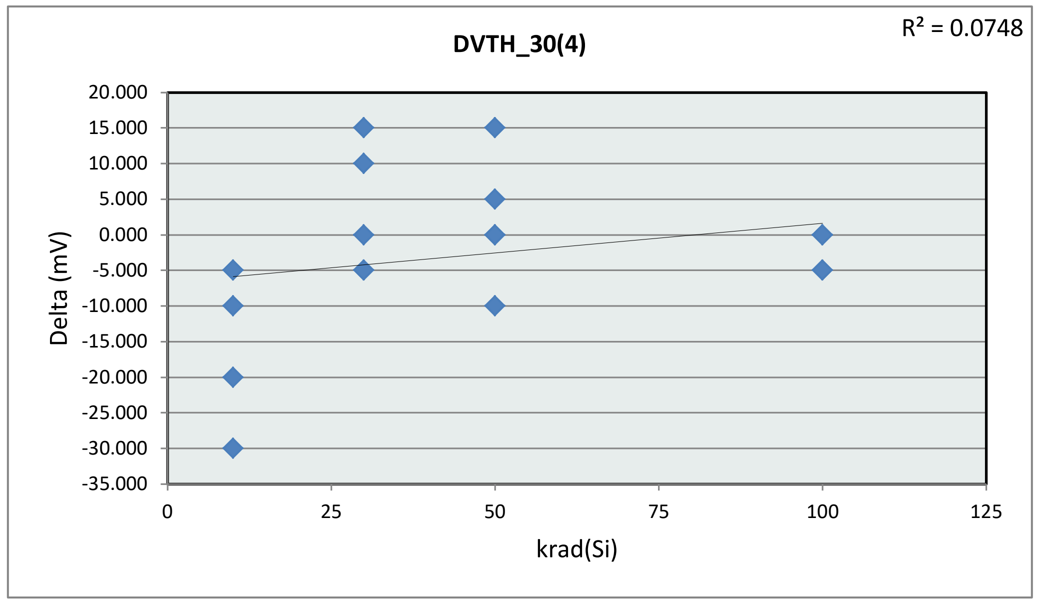


	VIDL_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-20.000	-5.000	-5.000	-15.000
Average	-11.000	-5.000	-5.000	-8.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

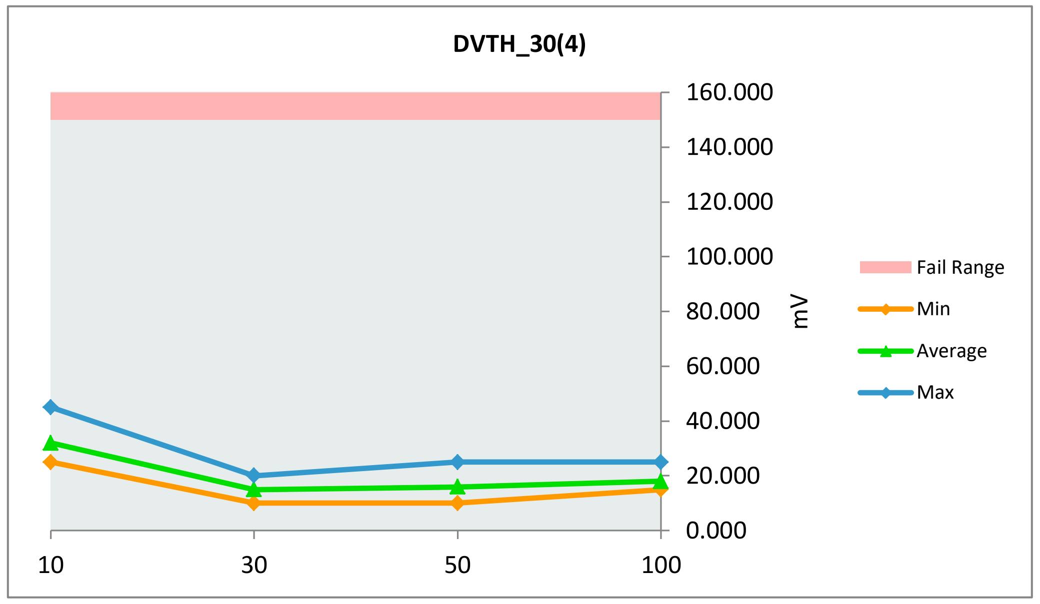


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_30(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	15.000	45.000	-30.000
10	7	20.000	25.000	-5.000
10	8	25.000	30.000	-5.000
10	9	15.000	25.000	-10.000
10	10	15.000	35.000	-20.000
30	6	15.000	15.000	0.000
30	7	20.000	10.000	10.000
30	8	25.000	10.000	15.000
30	9	15.000	20.000	-5.000
30	10	15.000	20.000	-5.000
50	6	15.000	25.000	-10.000
50	7	20.000	15.000	5.000
50	8	25.000	10.000	15.000
50	9	15.000	15.000	0.000
50	10	15.000	15.000	0.000
100	B011	25.000	25.000	0.000
100	B012	15.000	15.000	0.000
100	B013	10.000	15.000	-5.000
100	B014	15.000	20.000	-5.000
100	B015	15.000	15.000	0.000
	Max	25.000	45.000	15.000
	Average	17.500	20.250	-2.750
	Min	10.000	10.000	-30.000
	Std Dev	4.443	8.955	10.447

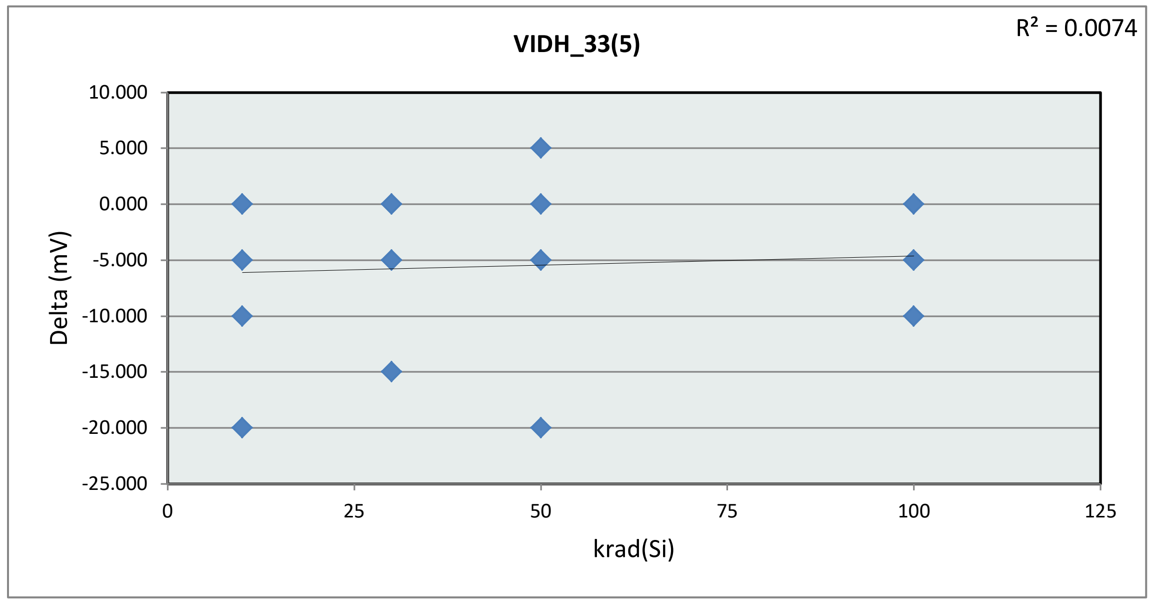


	DVTH_30(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	25.000	10.000	10.000	15.000
Average	32.000	15.000	16.000	18.000
Max	45.000	20.000	25.000	25.000
UL	150.000	150.000	150.000	150.000

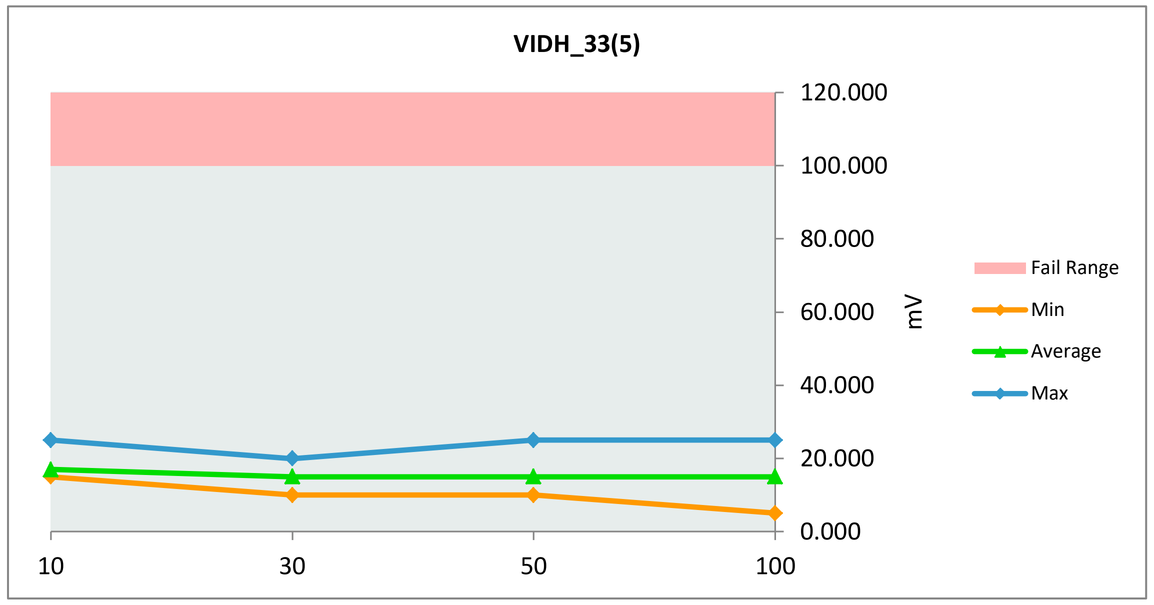


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	25.000	-20.000
10	7	10.000	15.000	-5.000
10	8	5.000	15.000	-10.000
10	9	15.000	15.000	0.000
10	10	15.000	15.000	0.000
30	6	5.000	20.000	-15.000
30	7	10.000	15.000	-5.000
30	8	5.000	10.000	-5.000
30	9	15.000	15.000	0.000
30	10	15.000	15.000	0.000
50	6	5.000	25.000	-20.000
50	7	10.000	15.000	-5.000
50	8	5.000	10.000	-5.000
50	9	15.000	15.000	0.000
50	10	15.000	10.000	5.000
100	B011	15.000	25.000	-10.000
100	B012	20.000	25.000	-5.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	10.000	-5.000
	Max	20.000	25.000	5.000
	Average	10.000	15.500	-5.500
	Min	5.000	5.000	-20.000
	Std Dev	5.130	5.826	6.669

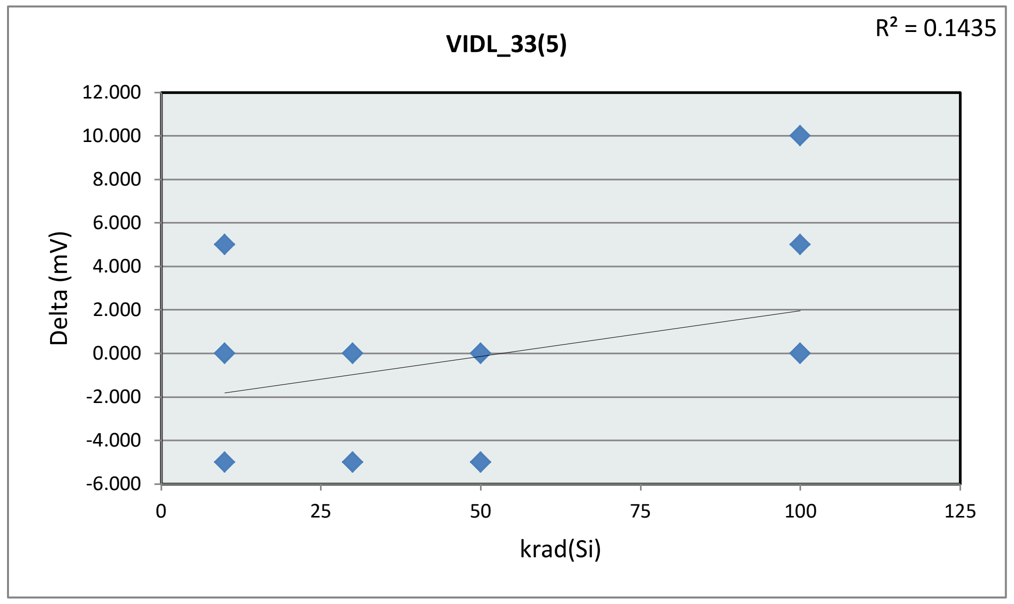


	VIDH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	10.000	5.000
Average	17.000	15.000	15.000	15.000
Max	25.000	20.000	25.000	25.000
UL	100.000	100.000	100.000	100.000

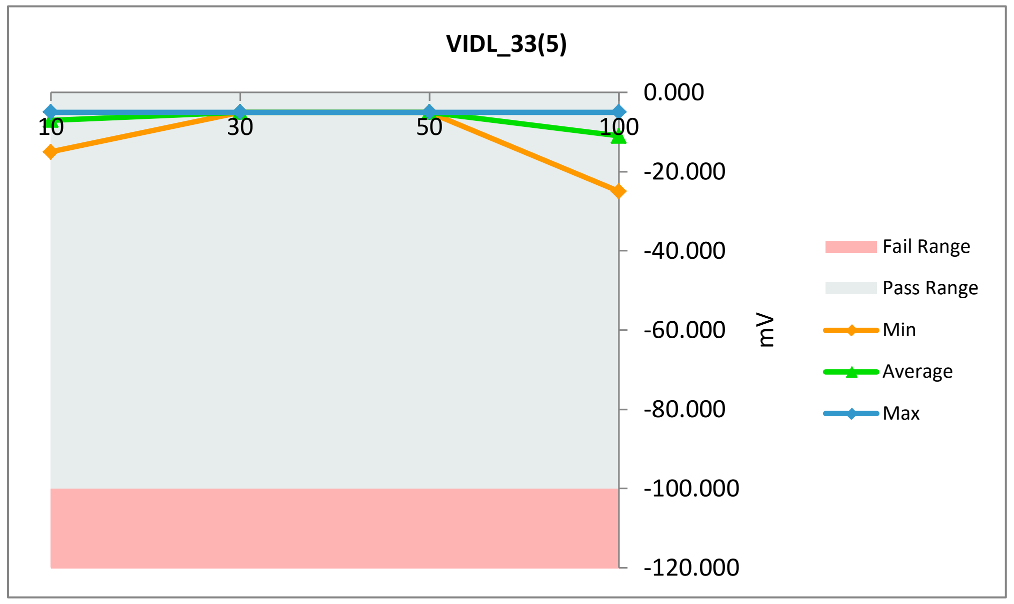


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_33(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-5.000	-5.000	0.000
10	8	-10.000	-15.000	5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-10.000	-5.000	-5.000
30	7	-5.000	-5.000	0.000
30	8	-10.000	-5.000	-5.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-10.000	-5.000	-5.000
50	7	-5.000	-5.000	0.000
50	8	-10.000	-5.000	-5.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-10.000	5.000
100	B014	-15.000	-25.000	10.000
100	B015	-10.000	-10.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-7.250	-7.000	-0.250
	Min	-15.000	-25.000	-5.000
	Std Dev	3.024	4.974	3.796



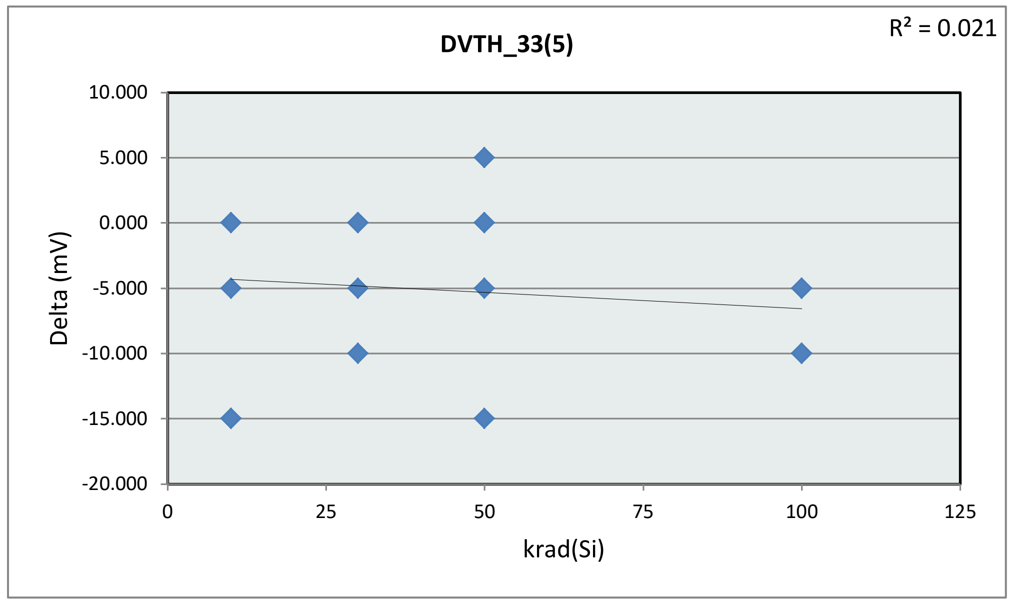
	VIDL_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-5.000	-5.000	-25.000
Average	-7.000	-5.000	-5.000	-11.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



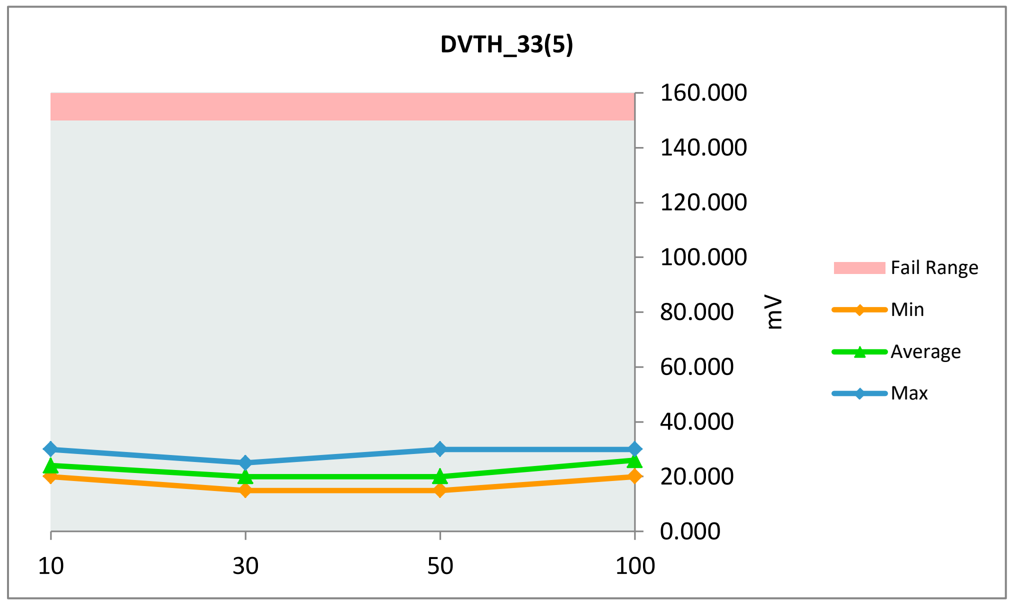
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_33(5)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	15.000	30.000	-15.000
10	7	15.000	20.000	-5.000
10	8	15.000	30.000	-15.000
10	9	20.000	20.000	0.000
10	10	20.000	20.000	0.000
30	6	15.000	25.000	-10.000
30	7	15.000	20.000	-5.000
30	8	15.000	15.000	0.000
30	9	20.000	20.000	0.000
30	10	20.000	20.000	0.000
50	6	15.000	30.000	-15.000
50	7	15.000	20.000	-5.000
50	8	15.000	15.000	0.000
50	9	20.000	20.000	0.000
50	10	20.000	15.000	5.000
100	B011	20.000	30.000	-10.000
100	B012	25.000	30.000	-5.000
100	B013	10.000	20.000	-10.000
100	B014	20.000	30.000	-10.000
100	B015	15.000	20.000	-5.000
	Max	25.000	30.000	5.000
	Average	17.250	22.500	-5.250
	Min	10.000	15.000	-15.000
	Std Dev	3.432	5.501	5.955

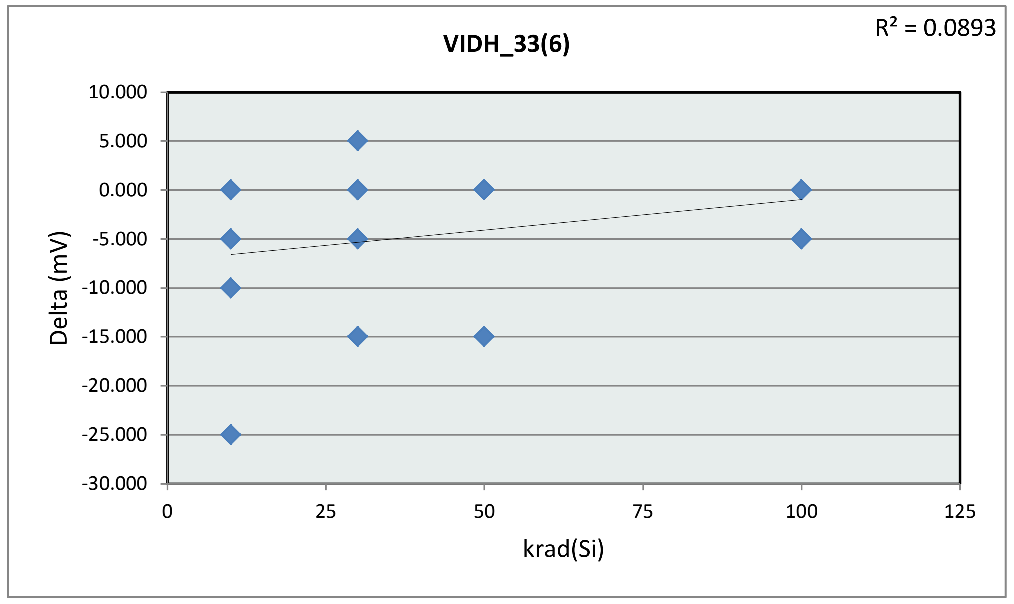


	DVTH_33(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	15.000	15.000	20.000
Average	24.000	20.000	20.000	26.000
Max	30.000	25.000	30.000	30.000
UL	150.000	150.000	150.000	150.000

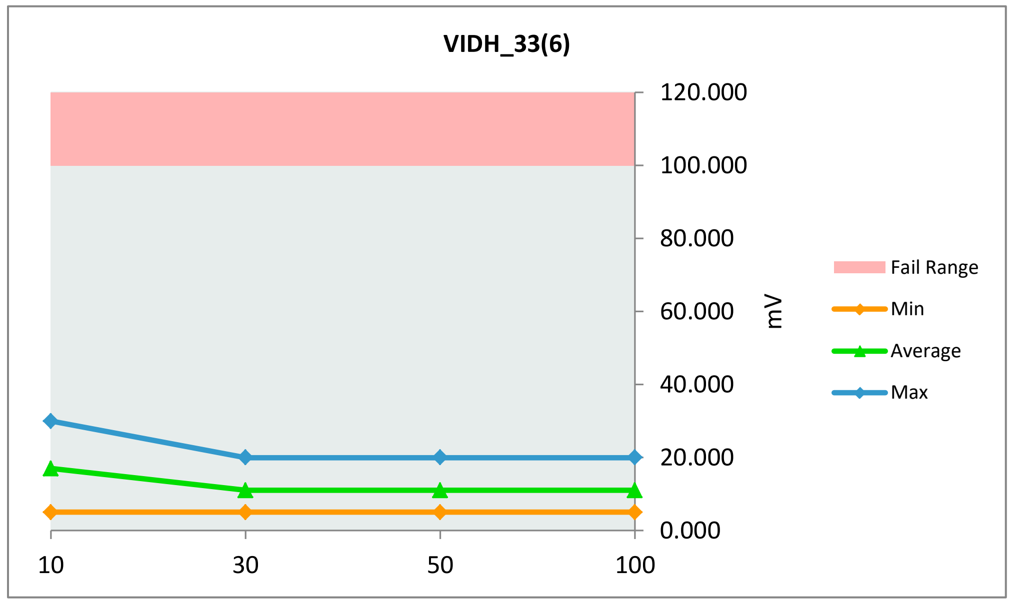


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	30.000	-25.000
10	7	10.000	15.000	-5.000
10	8	5.000	5.000	0.000
10	9	10.000	15.000	-5.000
10	10	10.000	20.000	-10.000
30	6	5.000	20.000	-15.000
30	7	10.000	5.000	5.000
30	8	5.000	5.000	0.000
30	9	10.000	10.000	0.000
30	10	10.000	15.000	-5.000
50	6	5.000	20.000	-15.000
50	7	10.000	10.000	0.000
50	8	5.000	5.000	0.000
50	9	10.000	10.000	0.000
50	10	10.000	10.000	0.000
100	B011	20.000	20.000	0.000
100	B012	10.000	15.000	-5.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	5.000	0.000
	Max	20.000	30.000	5.000
	Average	8.250	12.500	-4.250
	Min	5.000	5.000	-25.000
	Std Dev	3.726	6.977	7.122

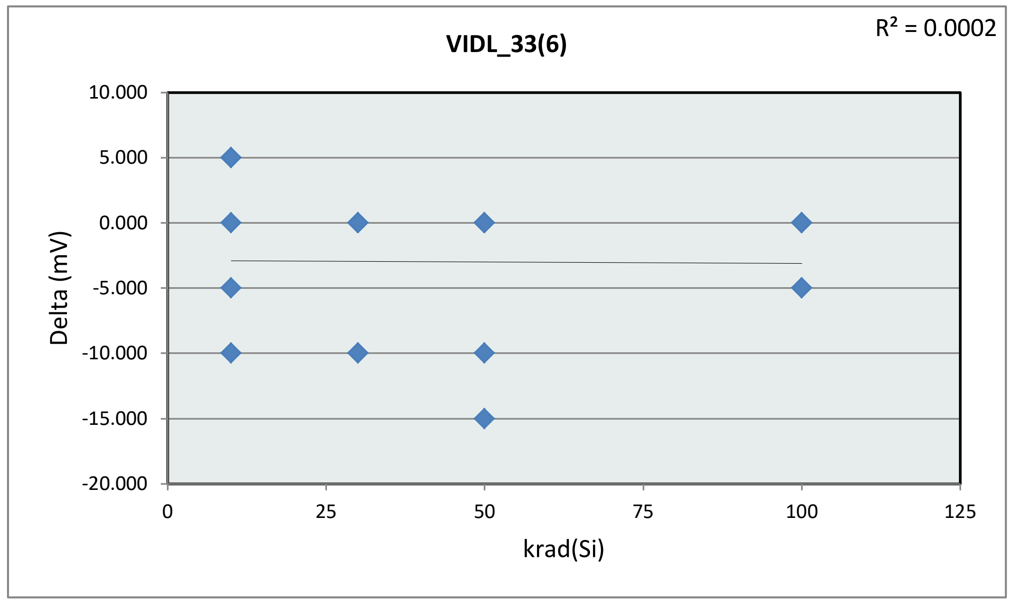


	VIDH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	17.000	11.000	11.000	11.000
Max	30.000	20.000	20.000	20.000
UL	100.000	100.000	100.000	100.000

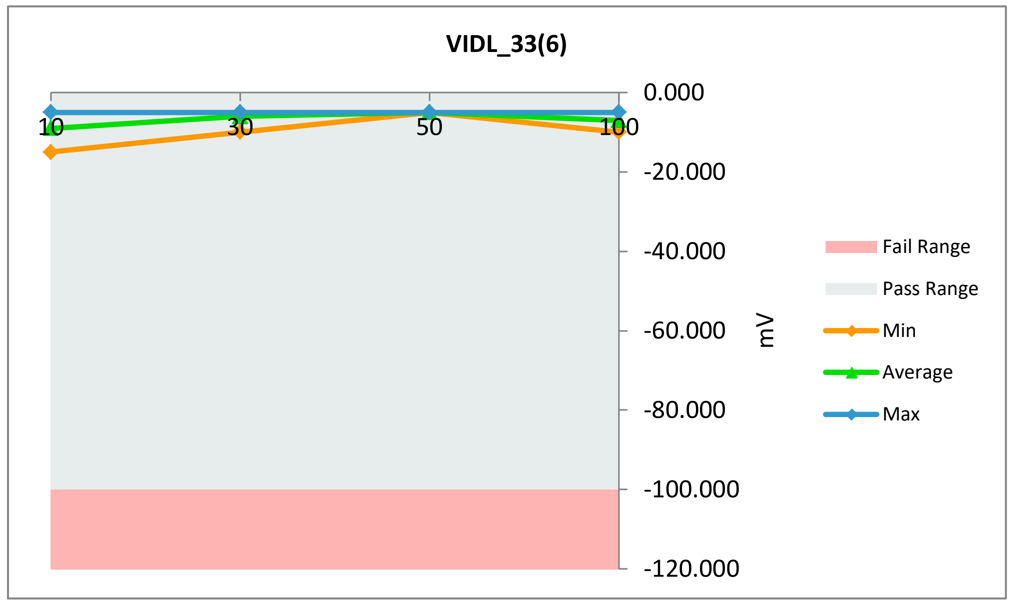


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_33(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-5.000	-10.000	5.000
10	8	-20.000	-15.000	-5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-10.000	5.000
30	6	-15.000	-5.000	-10.000
30	7	-5.000	-5.000	0.000
30	8	-20.000	-10.000	-10.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-15.000	-5.000	-10.000
50	7	-5.000	-5.000	0.000
50	8	-20.000	-5.000	-15.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-10.000	-5.000	-5.000
100	B014	-10.000	-10.000	0.000
100	B015	-15.000	-10.000	-5.000
	Max	-5.000	-5.000	5.000
	Average	-9.750	-6.750	-3.000
	Min	-20.000	-15.000	-15.000
	Std Dev	5.955	2.936	5.477



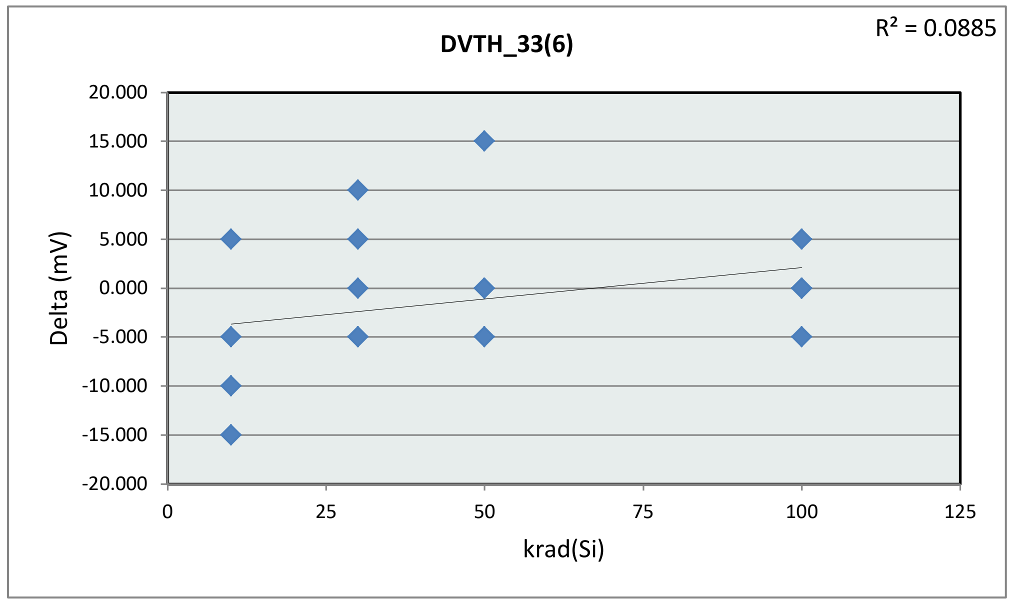
	VIDL_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-10.000	-5.000	-10.000
Average	-9.000	-6.000	-5.000	-7.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



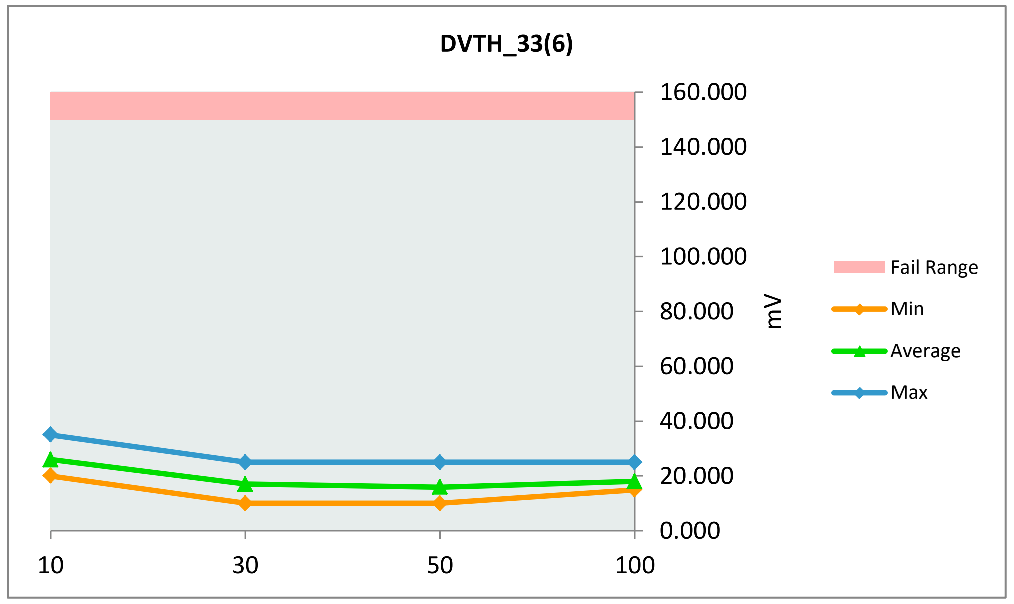
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_33(6)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	20.000	35.000	-15.000
10	7	15.000	25.000	-10.000
10	8	25.000	20.000	5.000
10	9	15.000	20.000	-5.000
10	10	15.000	30.000	-15.000
30	6	20.000	25.000	-5.000
30	7	15.000	10.000	5.000
30	8	25.000	15.000	10.000
30	9	15.000	15.000	0.000
30	10	15.000	20.000	-5.000
50	6	20.000	25.000	-5.000
50	7	15.000	15.000	0.000
50	8	25.000	10.000	15.000
50	9	15.000	15.000	0.000
50	10	15.000	15.000	0.000
100	B011	25.000	25.000	0.000
100	B012	15.000	20.000	-5.000
100	B013	15.000	15.000	0.000
100	B014	15.000	15.000	0.000
100	B015	20.000	15.000	5.000
	Max	25.000	35.000	15.000
	Average	18.000	19.250	-1.250
	Min	15.000	10.000	-15.000
	Std Dev	4.104	6.544	7.412

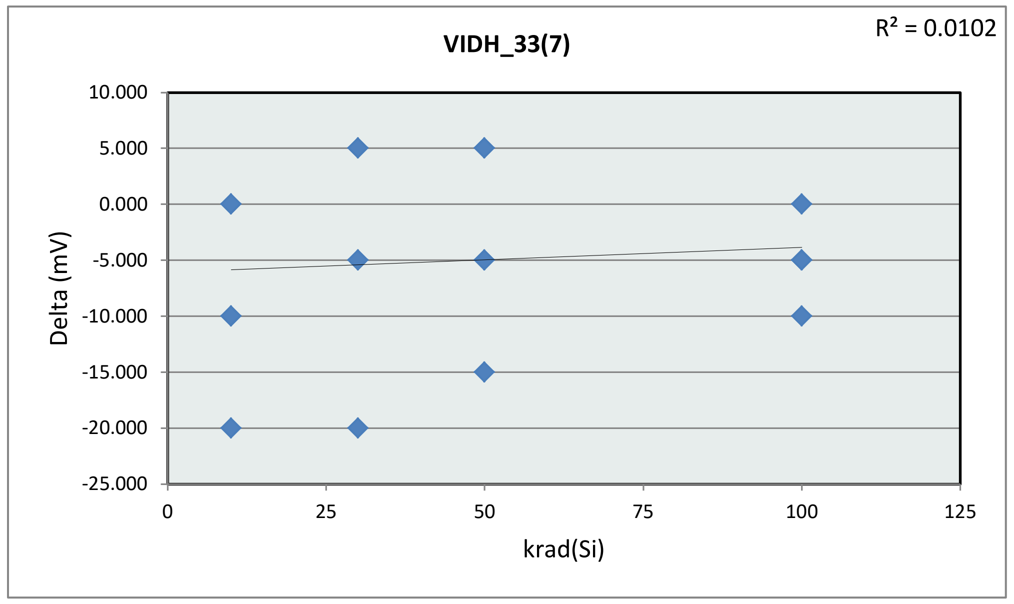


	DVTH_33(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	10.000	15.000
Average	26.000	17.000	16.000	18.000
Max	35.000	25.000	25.000	25.000
UL	150.000	150.000	150.000	150.000

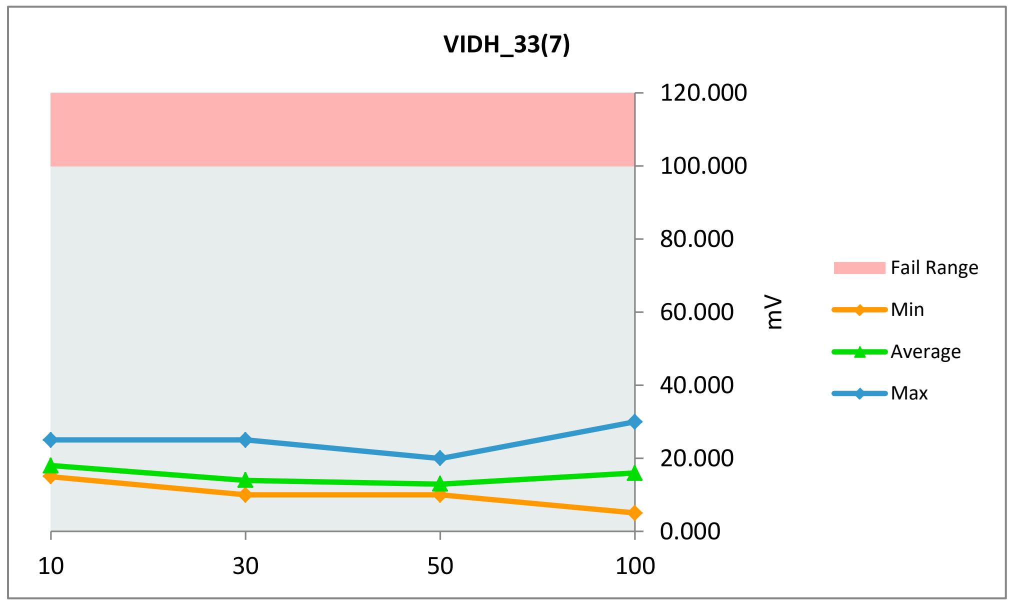


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		100	100	
Min Limit				
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	25.000	-20.000
10	7	10.000	20.000	-10.000
10	8	5.000	15.000	-10.000
10	9	15.000	15.000	0.000
10	10	15.000	15.000	0.000
30	6	5.000	25.000	-20.000
30	7	10.000	15.000	-5.000
30	8	5.000	10.000	-5.000
30	9	15.000	10.000	5.000
30	10	15.000	10.000	5.000
50	6	5.000	20.000	-15.000
50	7	10.000	15.000	-5.000
50	8	5.000	10.000	-5.000
50	9	15.000	10.000	5.000
50	10	15.000	10.000	5.000
100	B011	20.000	25.000	-5.000
100	B012	20.000	30.000	-10.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	10.000	-5.000
	Max	20.000	30.000	5.000
	Average	10.250	15.250	-5.000
	Min	5.000	5.000	-20.000
	Std Dev	5.495	6.781	7.609

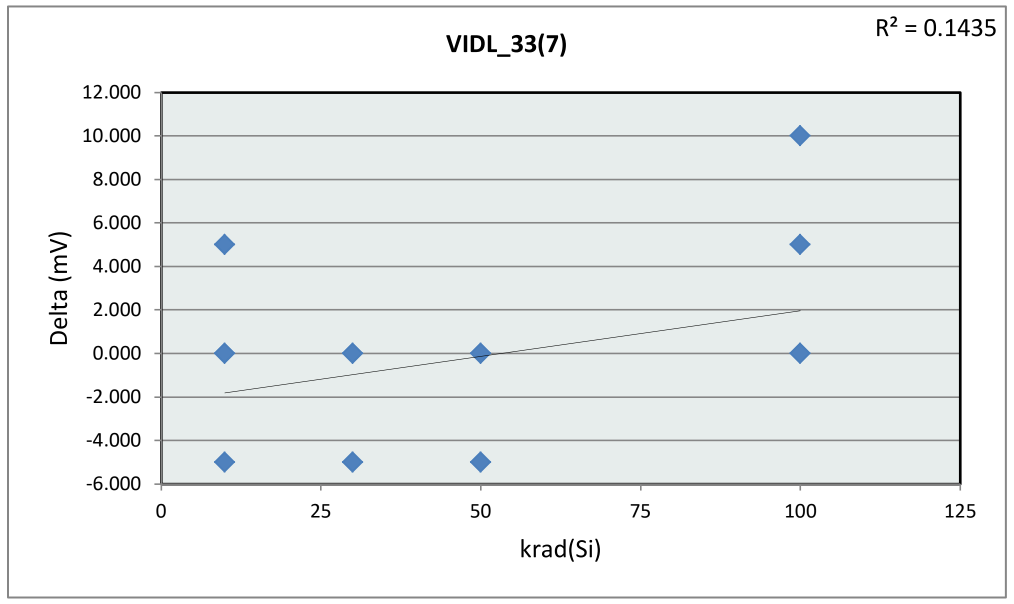


	VIDH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	10.000	5.000
Average	18.000	14.000	13.000	16.000
Max	25.000	25.000	20.000	30.000
UL	100.000	100.000	100.000	100.000

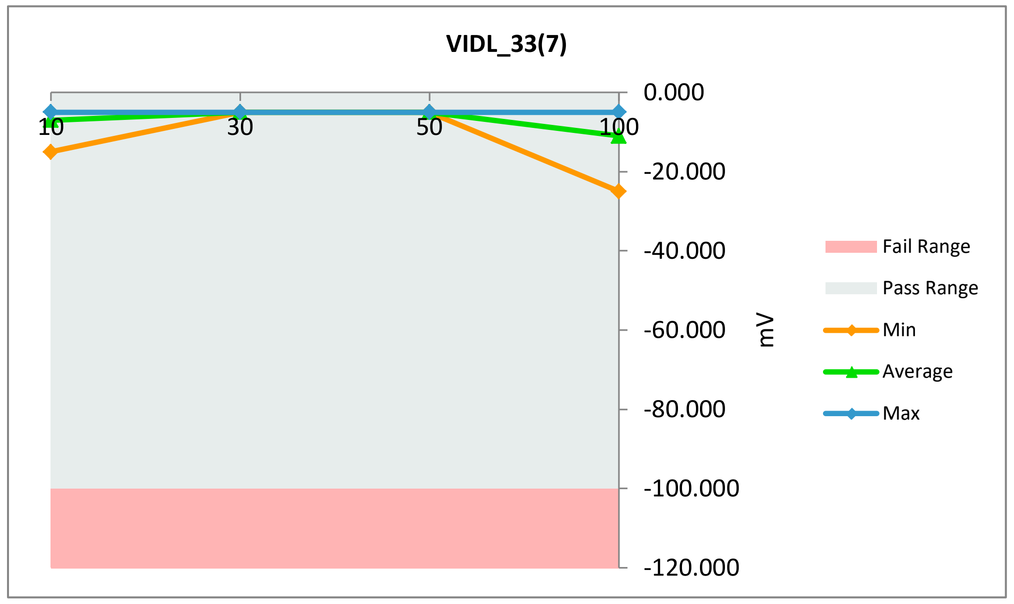


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-10.000	-5.000	-5.000
10	7	-5.000	-5.000	0.000
10	8	-10.000	-15.000	5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-10.000	-5.000	-5.000
30	7	-5.000	-5.000	0.000
30	8	-10.000	-5.000	-5.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-10.000	-5.000	-5.000
50	7	-5.000	-5.000	0.000
50	8	-10.000	-5.000	-5.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-10.000	5.000
100	B014	-15.000	-25.000	10.000
100	B015	-10.000	-10.000	0.000
	Max	-5.000	-5.000	10.000
	Average	-7.250	-7.000	-0.250
	Min	-15.000	-25.000	-5.000
	Std Dev	3.024	4.974	3.796

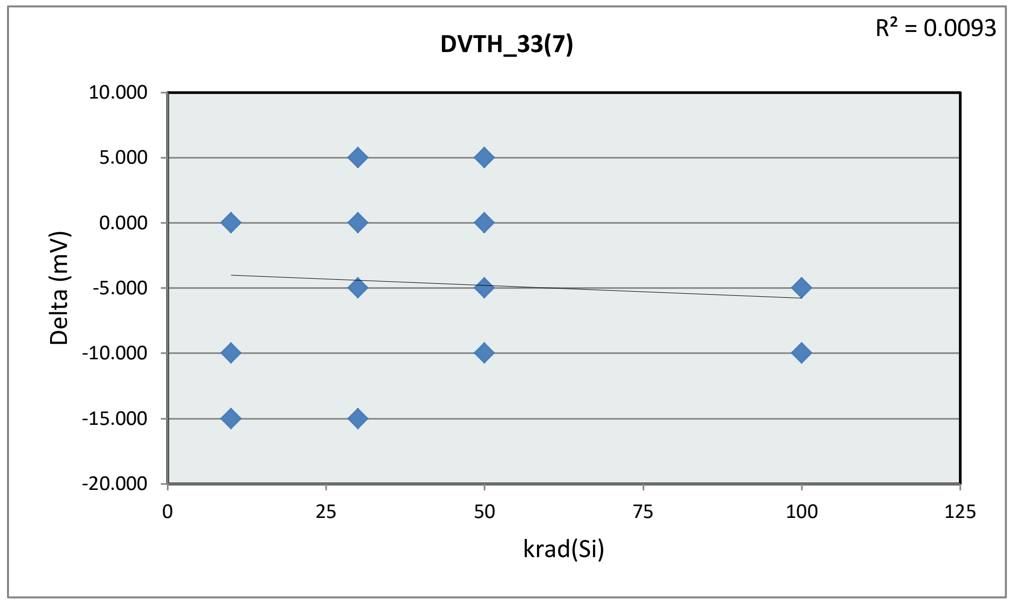


	VIDL_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-5.000	-5.000	-25.000
Average	-7.000	-5.000	-5.000	-11.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

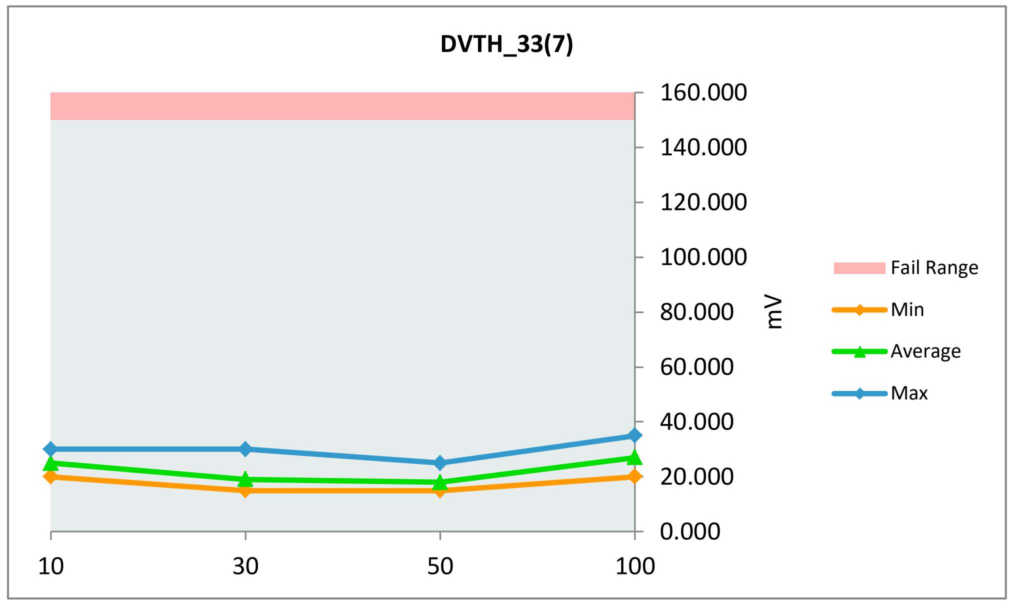


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_33(7)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		150	150	
Min Limit				
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	15.000	30.000	-15.000
10	7	15.000	25.000	-10.000
10	8	15.000	30.000	-15.000
10	9	20.000	20.000	0.000
10	10	20.000	20.000	0.000
30	6	15.000	30.000	-15.000
30	7	15.000	20.000	-5.000
30	8	15.000	15.000	0.000
30	9	20.000	15.000	5.000
30	10	20.000	15.000	5.000
50	6	15.000	25.000	-10.000
50	7	15.000	20.000	-5.000
50	8	15.000	15.000	0.000
50	9	20.000	15.000	5.000
50	10	20.000	15.000	5.000
100	B011	25.000	30.000	-5.000
100	B012	25.000	35.000	-10.000
100	B013	10.000	20.000	-10.000
100	B014	20.000	30.000	-10.000
100	B015	15.000	20.000	-5.000
	Max	25.000	35.000	5.000
	Average	17.500	22.250	-4.750
	Min	10.000	15.000	-15.000
	Std Dev	3.804	6.584	6.973



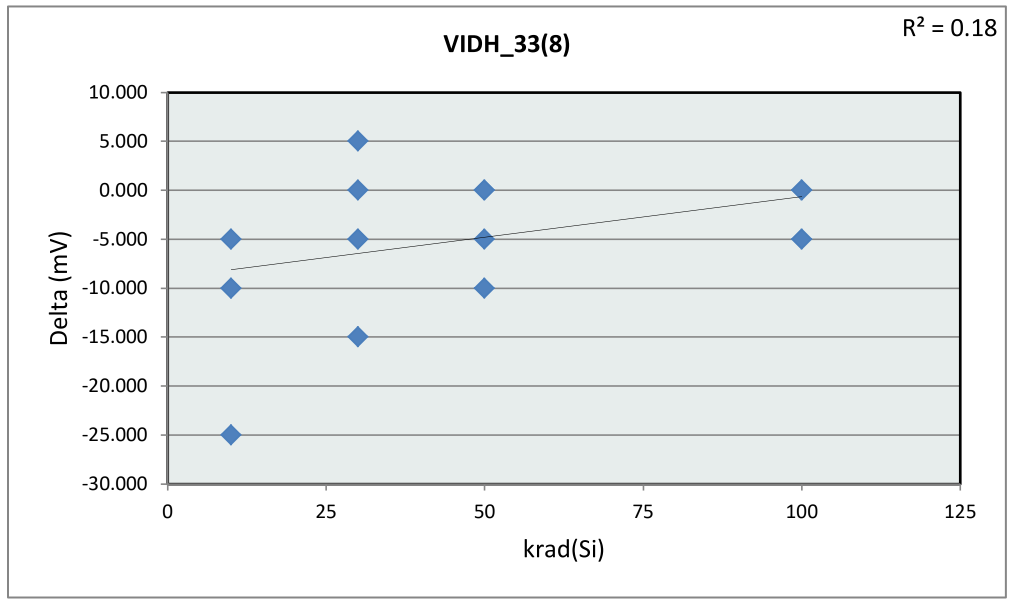
	DVTH_33(7)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	15.000	15.000	20.000
Average	25.000	19.000	18.000	27.000
Max	30.000	30.000	25.000	35.000
UL	150.000	150.000	150.000	150.000



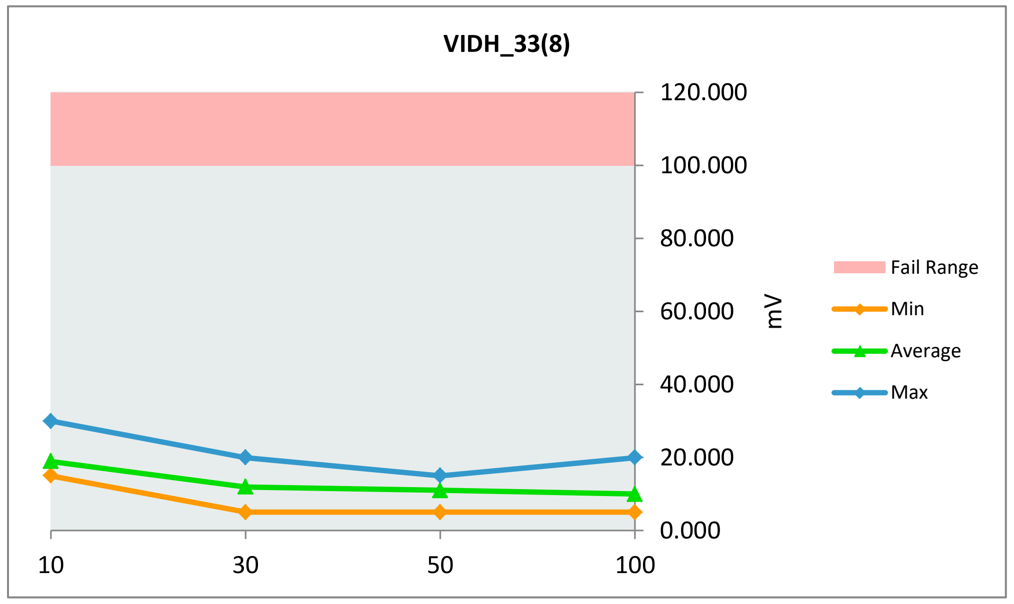
LDR UnBiased TID Report
SN55LVCP22A-SP

	VIDH_33(8)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	mV	mV	
Max Limit	100	100	
Min Limit			

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	5.000	30.000	-25.000
10	7	10.000	15.000	-5.000
10	8	5.000	15.000	-10.000
10	9	10.000	15.000	-5.000
10	10	10.000	20.000	-10.000
30	6	5.000	20.000	-15.000
30	7	10.000	15.000	-5.000
30	8	5.000	10.000	-5.000
30	9	10.000	10.000	0.000
30	10	10.000	5.000	5.000
50	6	5.000	15.000	-10.000
50	7	10.000	10.000	0.000
50	8	5.000	5.000	0.000
50	9	10.000	10.000	0.000
50	10	10.000	15.000	-5.000
100	B011	15.000	20.000	-5.000
100	B012	10.000	10.000	0.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	5.000	0.000
	Max	15.000	30.000	5.000
	Average	8.000	13.000	-5.000
	Min	5.000	5.000	-25.000
	Std Dev	2.991	6.366	6.689

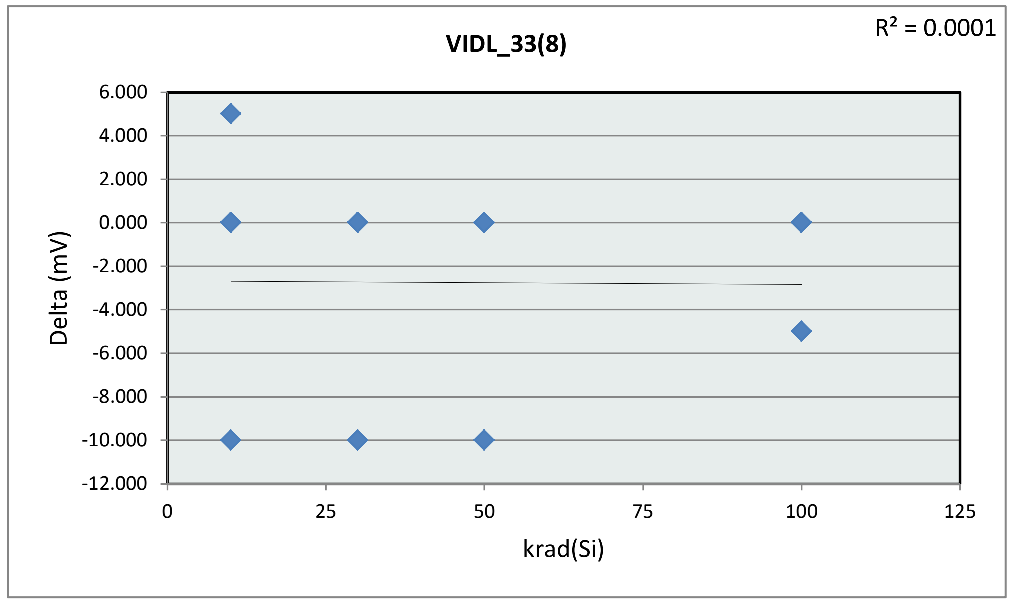


	VIDH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	5.000	5.000	5.000
Average	19.000	12.000	11.000	10.000
Max	30.000	20.000	15.000	20.000
UL	100.000	100.000	100.000	100.000

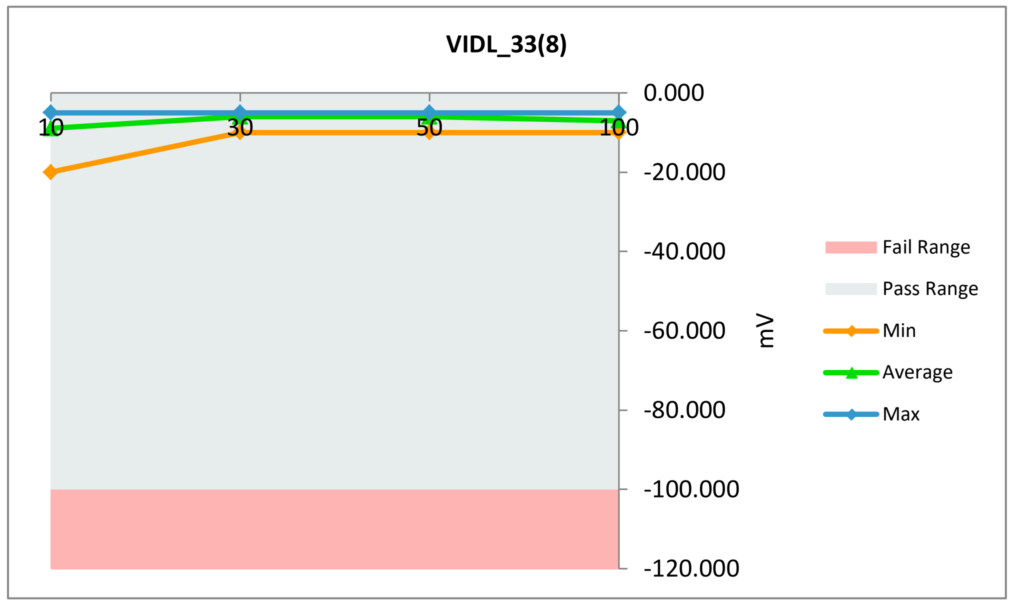


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_33(8)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-5.000	-10.000	5.000
10	8	-20.000	-20.000	0.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-15.000	-5.000	-10.000
30	7	-5.000	-5.000	0.000
30	8	-20.000	-10.000	-10.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-15.000	-5.000	-10.000
50	7	-5.000	-5.000	0.000
50	8	-20.000	-10.000	-10.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-5.000	0.000
100	B014	-15.000	-10.000	-5.000
100	B015	-15.000	-10.000	-5.000
	Max	-5.000	-5.000	5.000
	Average	-9.750	-7.000	-2.750
	Min	-20.000	-20.000	-10.000
	Std Dev	6.172	3.770	4.723



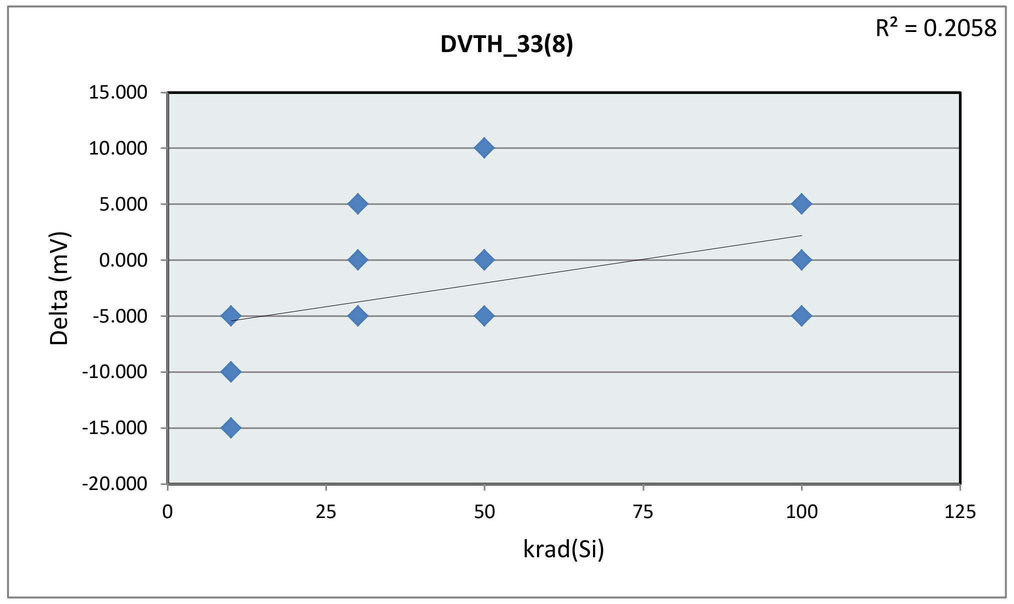
	VIDL_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-20.000	-10.000	-10.000	-10.000
Average	-9.000	-6.000	-6.000	-7.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



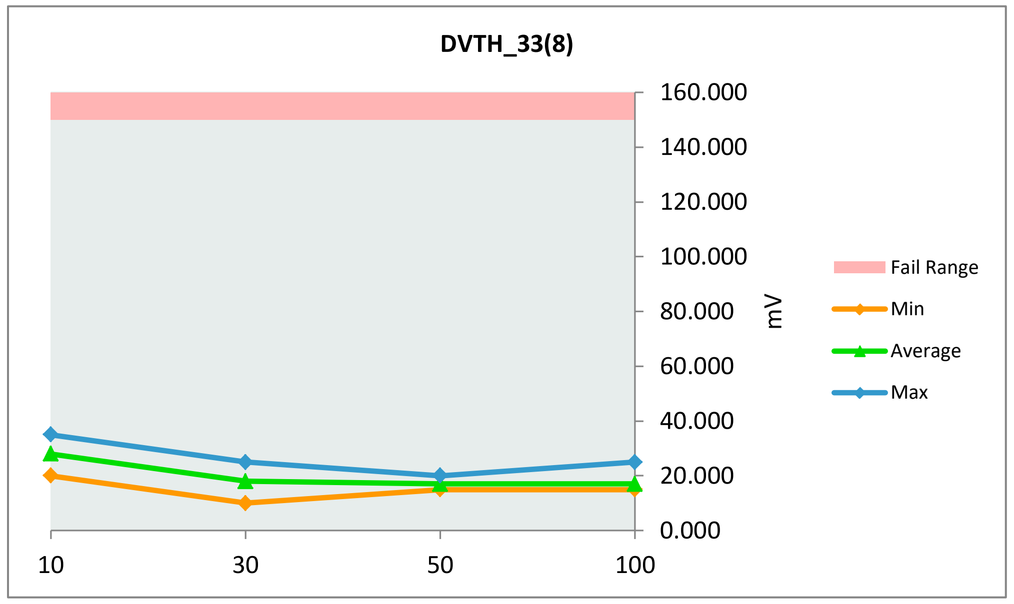
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_33(8)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	20.000	35.000	-15.000
10	7	15.000	25.000	-10.000
10	8	25.000	35.000	-10.000
10	9	15.000	20.000	-5.000
10	10	15.000	25.000	-10.000
30	6	20.000	25.000	-5.000
30	7	15.000	20.000	-5.000
30	8	25.000	20.000	5.000
30	9	15.000	15.000	0.000
30	10	15.000	10.000	5.000
50	6	20.000	20.000	0.000
50	7	15.000	15.000	0.000
50	8	25.000	15.000	10.000
50	9	15.000	15.000	0.000
50	10	15.000	20.000	-5.000
100	B011	20.000	25.000	-5.000
100	B012	15.000	15.000	0.000
100	B013	10.000	15.000	-5.000
100	B014	20.000	15.000	5.000
100	B015	20.000	15.000	5.000
	Max	25.000	35.000	10.000
	Average	17.750	20.000	-2.250
	Min	10.000	10.000	-15.000
	Std Dev	4.128	6.689	6.382

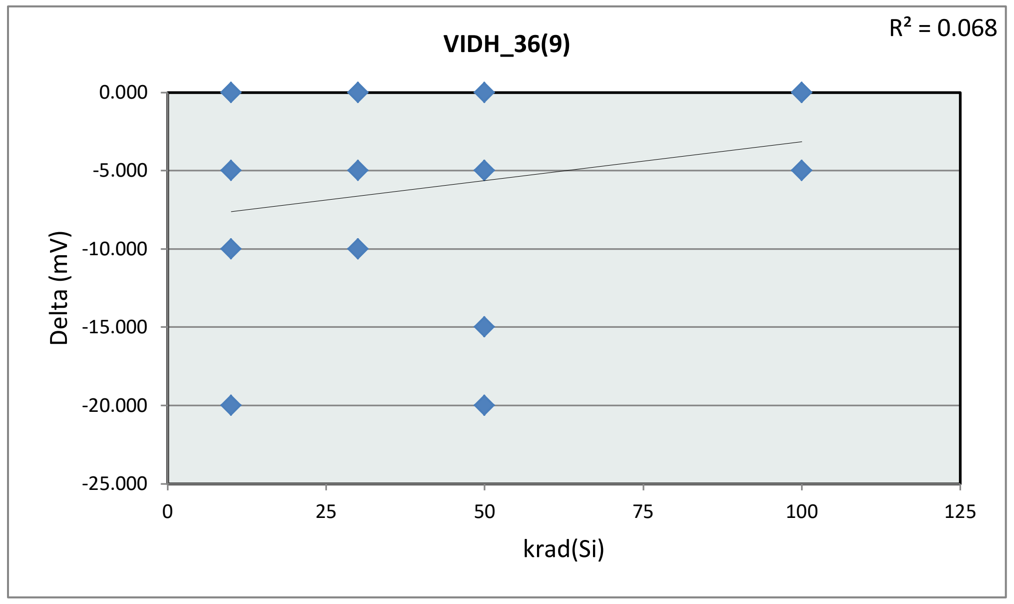


	DVTH_33(8)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	15.000	15.000
Average	28.000	18.000	17.000	17.000
Max	35.000	25.000	20.000	25.000
UL	150.000	150.000	150.000	150.000

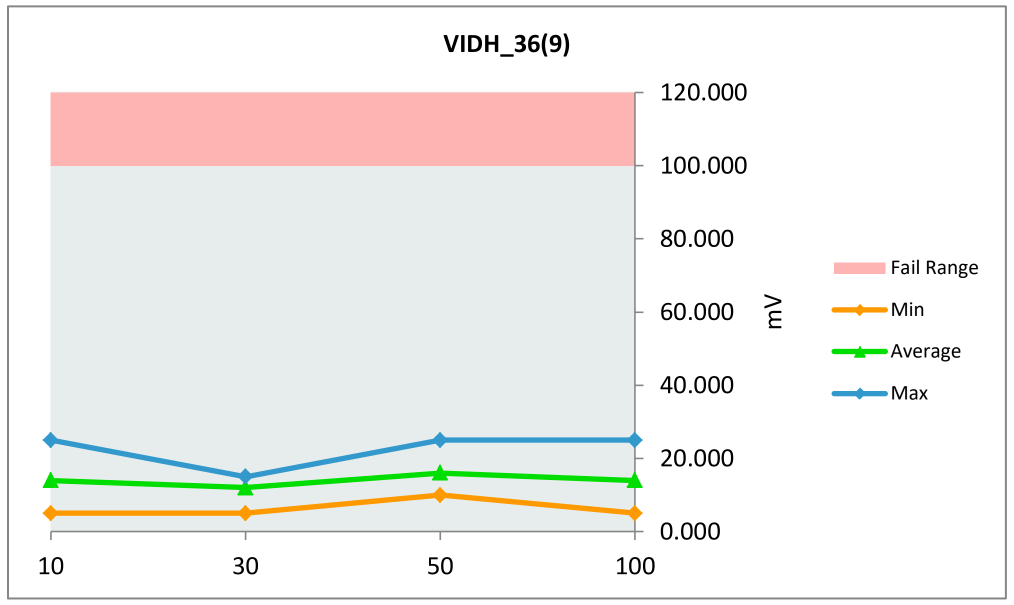


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	25.000	-20.000
10	7	5.000	15.000	-10.000
10	8	5.000	5.000	0.000
10	9	10.000	15.000	-5.000
10	10	10.000	10.000	0.000
30	6	5.000	15.000	-10.000
30	7	5.000	15.000	-10.000
30	8	5.000	5.000	0.000
30	9	10.000	15.000	-5.000
30	10	10.000	10.000	0.000
50	6	5.000	25.000	-20.000
50	7	5.000	20.000	-15.000
50	8	5.000	10.000	-5.000
50	9	10.000	15.000	-5.000
50	10	10.000	10.000	0.000
100	B011	20.000	20.000	0.000
100	B012	25.000	25.000	0.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	10.000	-5.000
	Max	25.000	25.000	0.000
	Average	8.250	14.000	-5.750
	Min	5.000	5.000	-20.000
	Std Dev	5.447	6.407	6.544

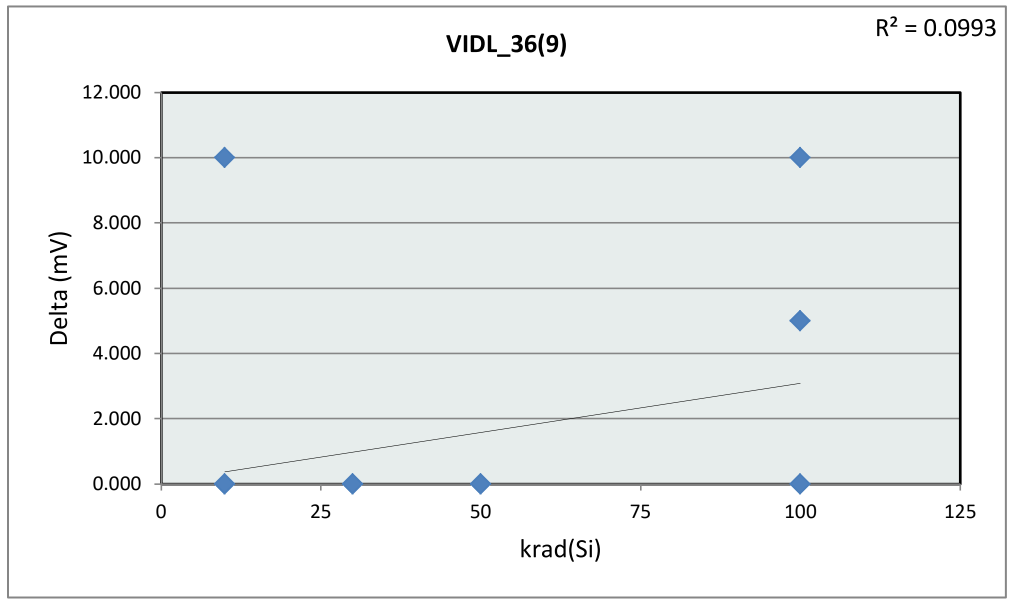


	VIDH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	10.000	5.000
Average	14.000	12.000	16.000	14.000
Max	25.000	15.000	25.000	25.000
UL	100.000	100.000	100.000	100.000

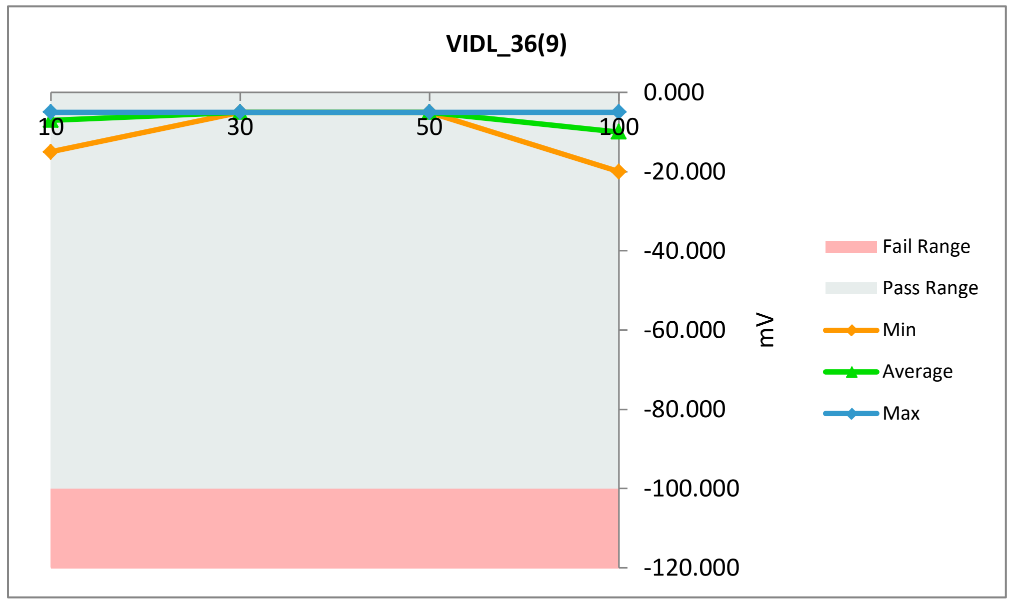


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_36(9)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit			
	Min Limit	-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-5.000	-5.000	0.000
10	7	-5.000	-5.000	0.000
10	8	-5.000	-15.000	10.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-5.000	-5.000	0.000
30	8	-5.000	-5.000	0.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-5.000	-5.000	0.000
50	7	-5.000	-5.000	0.000
50	8	-5.000	-5.000	0.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-10.000	5.000
100	B014	-10.000	-20.000	10.000
100	B015	-5.000	-10.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-5.250	-6.750	1.500
	Min	-10.000	-20.000	0.000
	Std Dev	1.118	4.064	3.285



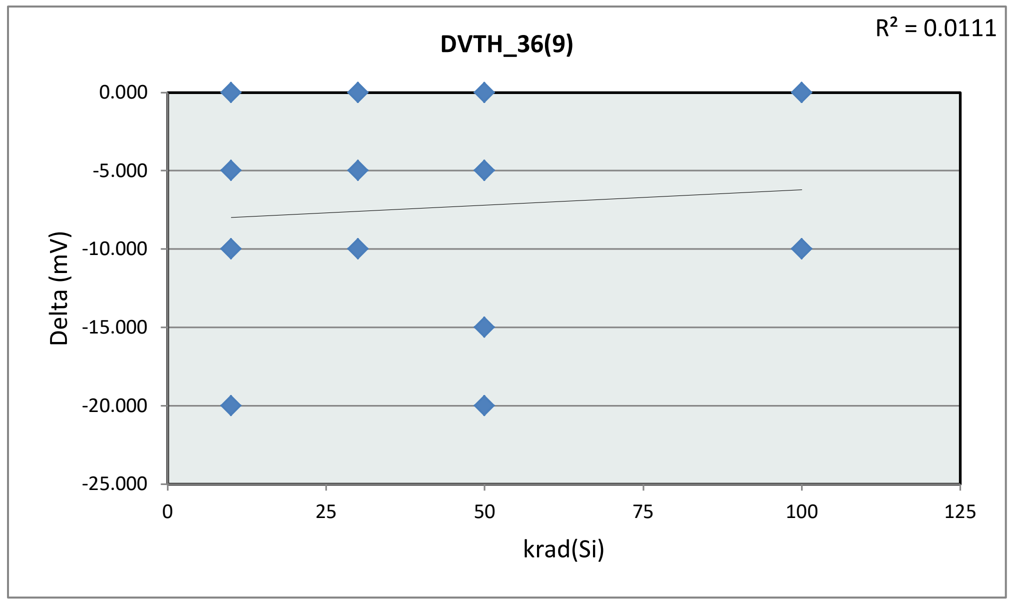
	VIDL_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-5.000	-5.000	-20.000
Average	-7.000	-5.000	-5.000	-10.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



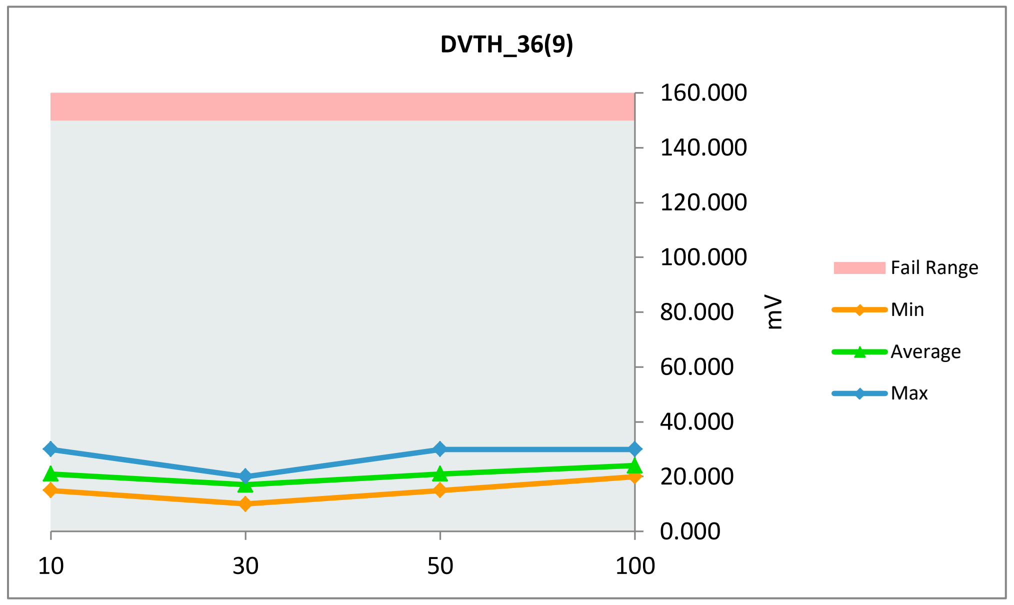
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_36(9)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	10.000	30.000	-20.000
10	7	10.000	20.000	-10.000
10	8	10.000	20.000	-10.000
10	9	15.000	20.000	-5.000
10	10	15.000	15.000	0.000
30	6	10.000	20.000	-10.000
30	7	10.000	20.000	-10.000
30	8	10.000	10.000	0.000
30	9	15.000	20.000	-5.000
30	10	15.000	15.000	0.000
50	6	10.000	30.000	-20.000
50	7	10.000	25.000	-15.000
50	8	10.000	15.000	-5.000
50	9	15.000	20.000	-5.000
50	10	15.000	15.000	0.000
100	B011	25.000	25.000	0.000
100	B012	30.000	30.000	0.000
100	B013	10.000	20.000	-10.000
100	B014	15.000	25.000	-10.000
100	B015	10.000	20.000	-10.000
	Max	30.000	30.000	0.000
	Average	13.500	20.750	-7.250
	Min	10.000	10.000	-20.000
	Std Dev	5.405	5.447	6.382

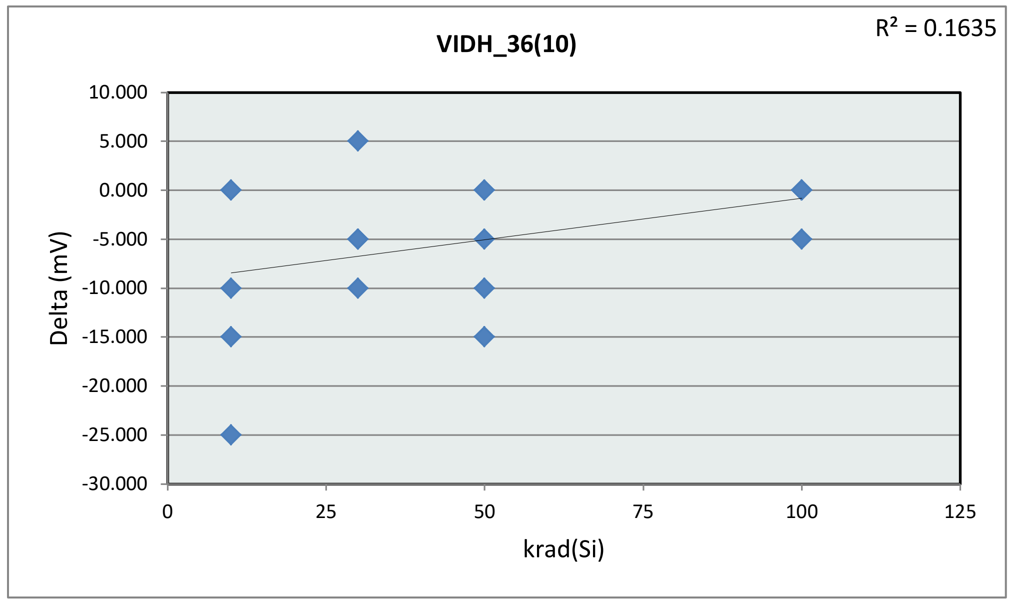


	DVTH_36(9)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	15.000	10.000	15.000	20.000
Average	21.000	17.000	21.000	24.000
Max	30.000	20.000	30.000	30.000
UL	150.000	150.000	150.000	150.000

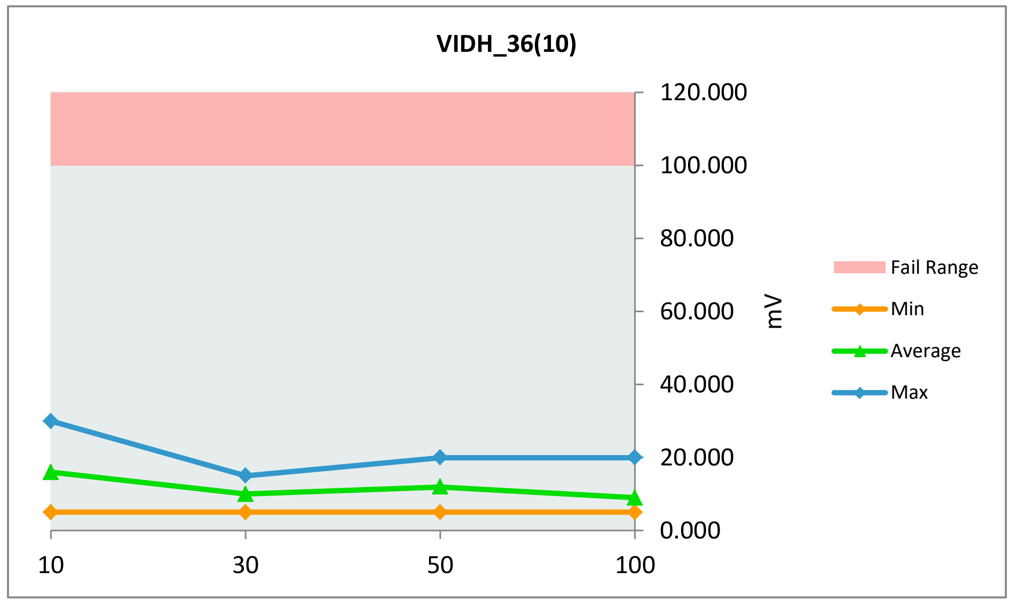


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit			
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	5.000	30.000	-25.000
10	7	10.000	10.000	0.000
10	8	5.000	5.000	0.000
10	9	5.000	15.000	-10.000
10	10	5.000	20.000	-15.000
30	6	5.000	10.000	-5.000
30	7	10.000	5.000	5.000
30	8	5.000	10.000	-5.000
30	9	5.000	15.000	-10.000
30	10	5.000	10.000	-5.000
50	6	5.000	20.000	-15.000
50	7	10.000	10.000	0.000
50	8	5.000	5.000	0.000
50	9	5.000	10.000	-5.000
50	10	5.000	15.000	-10.000
100	B011	15.000	20.000	-5.000
100	B012	10.000	10.000	0.000
100	B013	5.000	5.000	0.000
100	B014	5.000	5.000	0.000
100	B015	5.000	5.000	0.000
	Max	15.000	30.000	5.000
	Average	6.500	11.750	-5.250
	Min	5.000	5.000	-25.000
	Std Dev	2.856	6.742	7.159



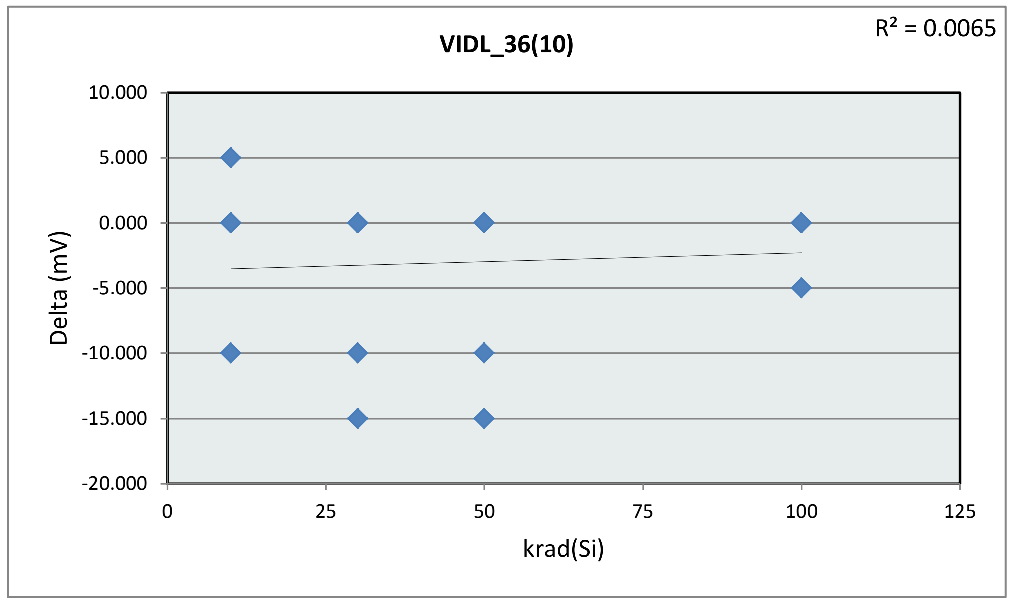
	VIDH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	5.000	5.000
Average	16.000	10.000	12.000	9.000
Max	30.000	15.000	20.000	20.000
UL	100.000	100.000	100.000	100.000



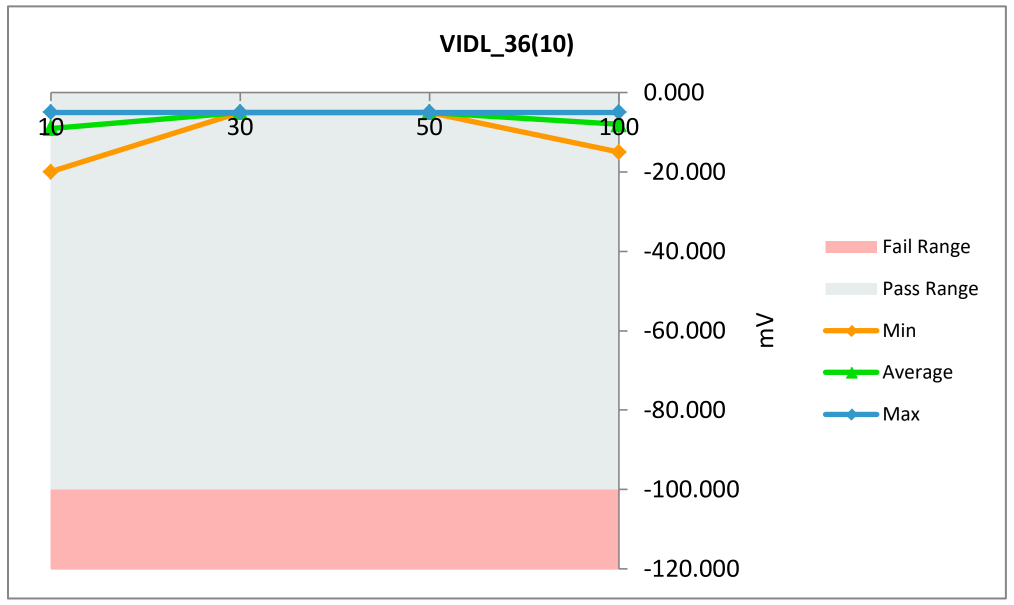
LDR UnBiased TID Report
SN55LVCP22A-SP

	VIDL_36(10)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-5.000	-10.000	5.000
10	8	-20.000	-20.000	0.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-15.000	-5.000	-10.000
30	7	-5.000	-5.000	0.000
30	8	-20.000	-5.000	-15.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-15.000	-5.000	-10.000
50	7	-5.000	-5.000	0.000
50	8	-20.000	-5.000	-15.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-5.000	0.000
100	B014	-15.000	-10.000	-5.000
100	B015	-15.000	-15.000	0.000
	Max	-5.000	-5.000	5.000
	Average	-9.750	-6.750	-3.000
	Min	-20.000	-20.000	-15.000
	Std Dev	6.172	4.064	5.712

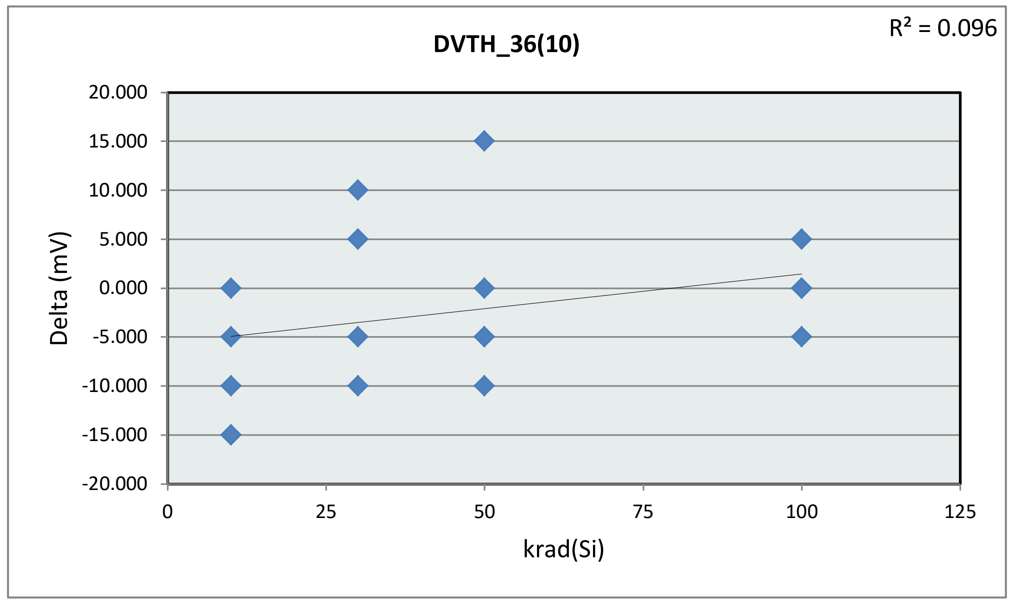


	VIDL_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	mV			
Min Limit	-100 mV			
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-20.000	-5.000	-5.000	-15.000
Average	-9.000	-5.000	-5.000	-8.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

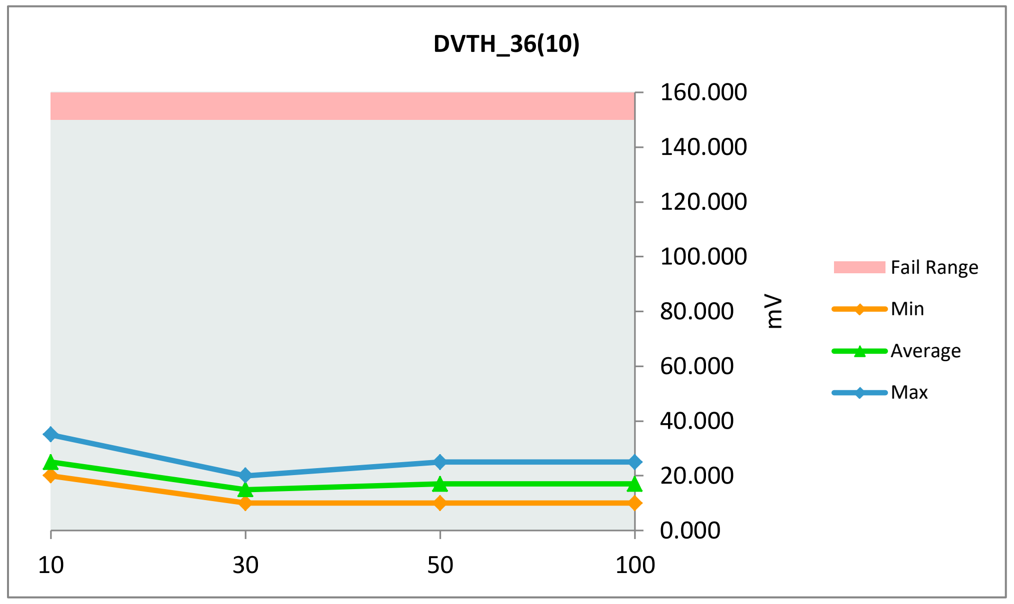


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_36(10)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	150	150	
	Min Limit			
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	20.000	35.000	-15.000
10	7	15.000	20.000	-5.000
10	8	25.000	25.000	0.000
10	9	10.000	20.000	-10.000
10	10	10.000	25.000	-15.000
30	6	20.000	15.000	5.000
30	7	15.000	10.000	5.000
30	8	25.000	15.000	10.000
30	9	10.000	20.000	-10.000
30	10	10.000	15.000	-5.000
50	6	20.000	25.000	-5.000
50	7	15.000	15.000	0.000
50	8	25.000	10.000	15.000
50	9	10.000	15.000	-5.000
50	10	10.000	20.000	-10.000
100	B011	20.000	25.000	-5.000
100	B012	15.000	15.000	0.000
100	B013	10.000	10.000	0.000
100	B014	20.000	15.000	5.000
100	B015	20.000	20.000	0.000
	Max	25.000	35.000	15.000
	Average	16.250	18.500	-2.250
	Min	10.000	10.000	-15.000
	Std Dev	5.590	6.304	7.860



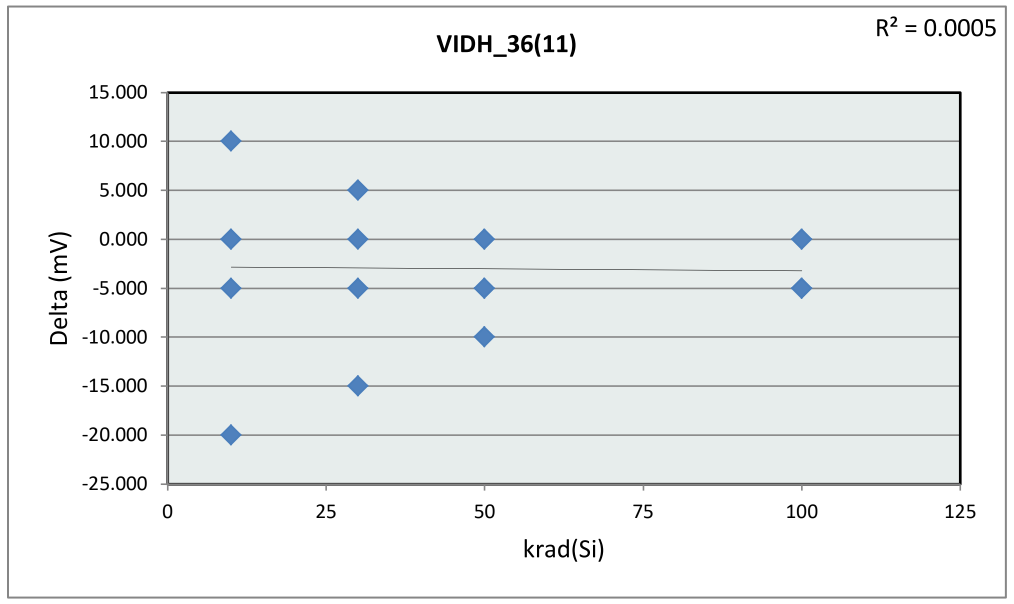
	DVTH_36(10)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	10.000	10.000	10.000
Average	25.000	15.000	17.000	17.000
Max	35.000	20.000	25.000	25.000
UL	150.000	150.000	150.000	150.000



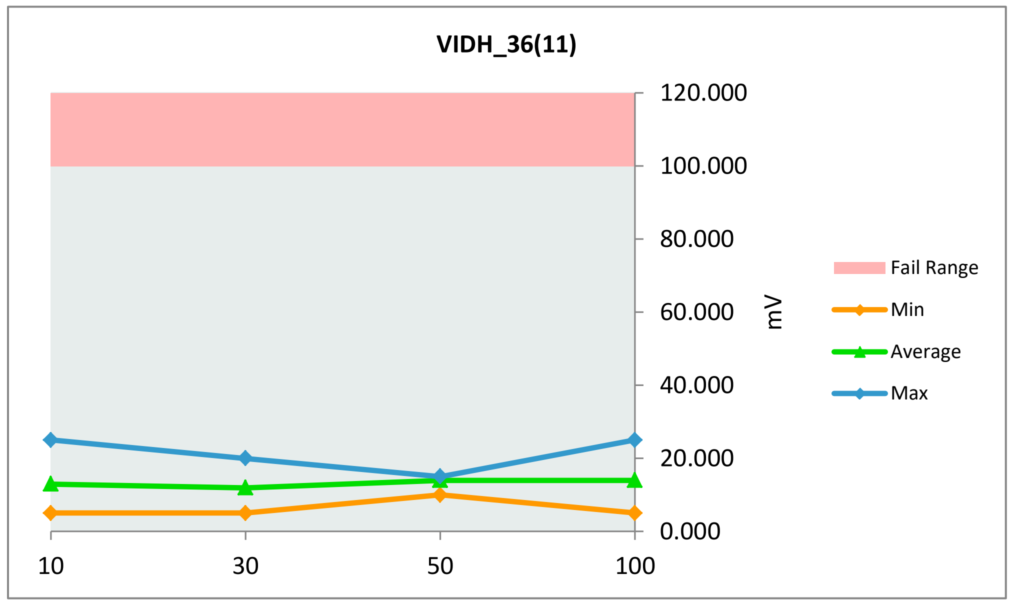
LDR UnBiased TID Report
SN55LVCP22A-SP

	VIDH_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	25.000	-20.000
10	7	10.000	15.000	-5.000
10	8	5.000	5.000	0.000
10	9	15.000	15.000	0.000
10	10	15.000	5.000	10.000
30	6	5.000	20.000	-15.000
30	7	10.000	15.000	-5.000
30	8	5.000	5.000	0.000
30	9	15.000	10.000	5.000
30	10	15.000	10.000	5.000
50	6	5.000	15.000	-10.000
50	7	10.000	15.000	-5.000
50	8	5.000	10.000	-5.000
50	9	15.000	15.000	0.000
50	10	15.000	15.000	0.000
100	B011	20.000	20.000	0.000
100	B012	20.000	25.000	-5.000
100	B013	5.000	10.000	-5.000
100	B014	5.000	5.000	0.000
100	B015	5.000	10.000	-5.000
	Max	20.000	25.000	10.000
	Average	10.250	13.250	-3.000
	Min	5.000	5.000	-20.000
	Std Dev	5.495	6.129	6.767



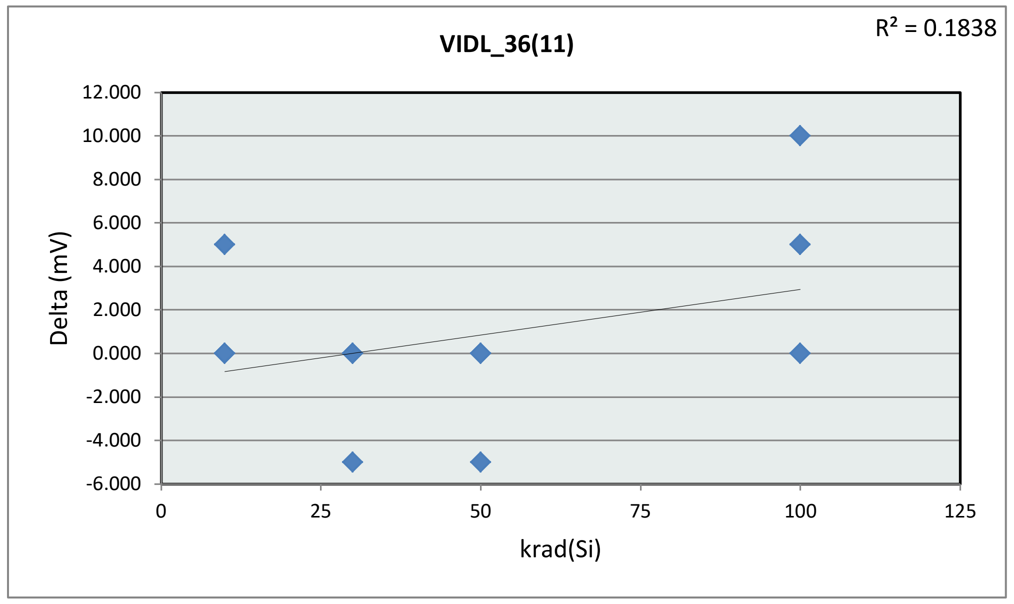
	VIDH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	100	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	5.000	5.000	10.000	5.000
Average	13.000	12.000	14.000	14.000
Max	25.000	20.000	15.000	25.000
UL	100.000	100.000	100.000	100.000



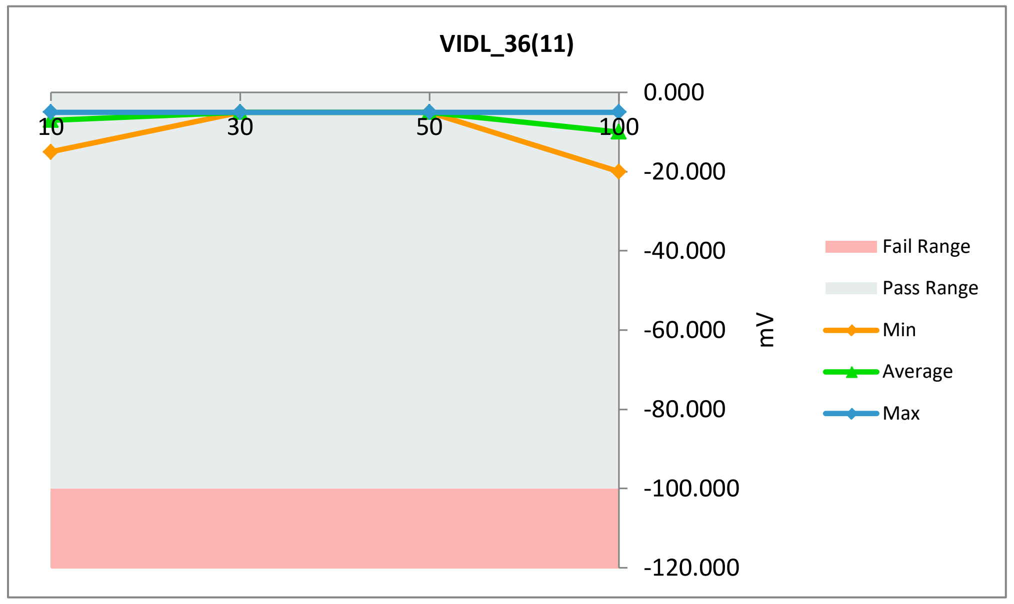
LDR UnBiased TID Report
SN55LVCP22A-SP

	VIDL_36(11)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit		
Min Limit	-100	-100

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-5.000	-5.000	0.000
10	7	-5.000	-5.000	0.000
10	8	-10.000	-15.000	5.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-5.000	-5.000	0.000
30	7	-5.000	-5.000	0.000
30	8	-10.000	-5.000	-5.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-5.000	-5.000	0.000
50	7	-5.000	-5.000	0.000
50	8	-10.000	-5.000	-5.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-10.000	5.000
100	B014	-10.000	-20.000	10.000
100	B015	-5.000	-10.000	5.000
	Max	-5.000	-5.000	10.000
	Average	-6.000	-6.750	0.750
	Min	-10.000	-20.000	-5.000
	Std Dev	2.052	4.064	3.354

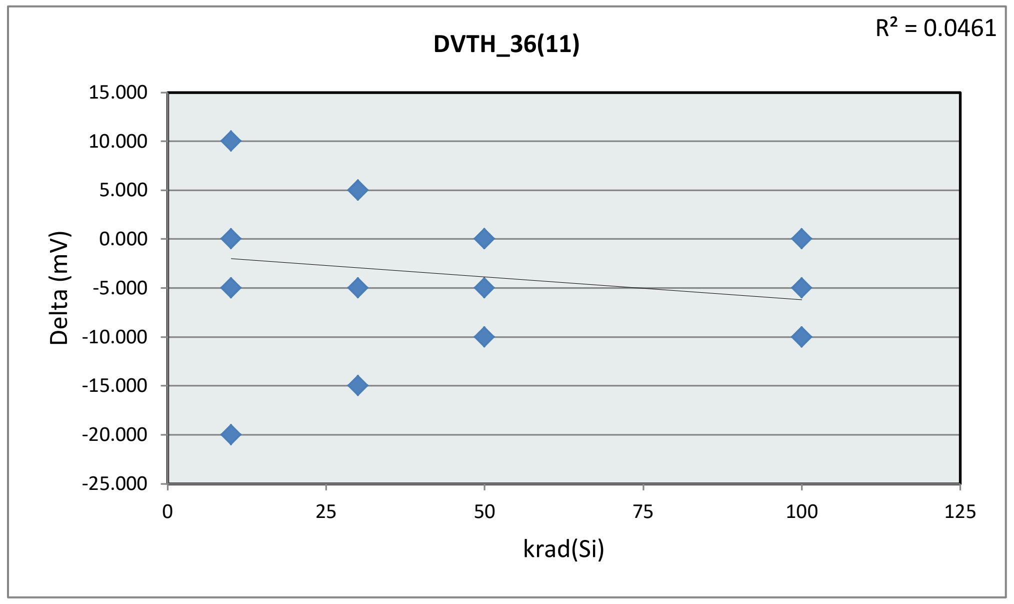


	VIDL_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-15.000	-5.000	-5.000	-20.000
Average	-7.000	-5.000	-5.000	-10.000
Max	-5.000	-5.000	-5.000	-5.000
UL				

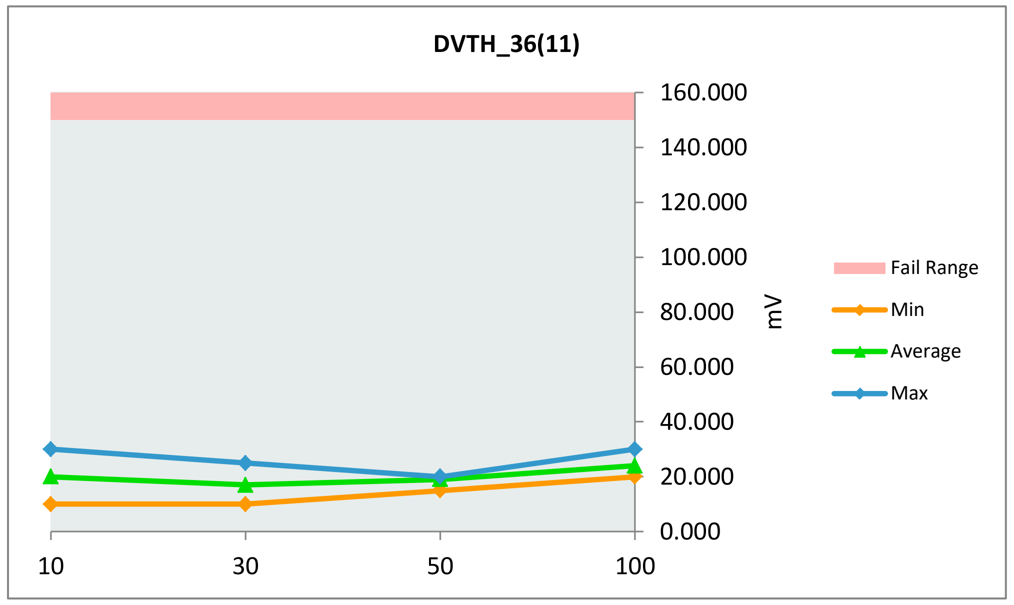


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVTH_36(11)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit		150	150	
Min Limit				
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	10.000	30.000	-20.000
10	7	15.000	20.000	-5.000
10	8	15.000	20.000	-5.000
10	9	20.000	20.000	0.000
10	10	20.000	10.000	10.000
30	6	10.000	25.000	-15.000
30	7	15.000	20.000	-5.000
30	8	15.000	10.000	5.000
30	9	20.000	15.000	5.000
30	10	20.000	15.000	5.000
50	6	10.000	20.000	-10.000
50	7	15.000	20.000	-5.000
50	8	15.000	15.000	0.000
50	9	20.000	20.000	0.000
50	10	20.000	20.000	0.000
100	B011	25.000	25.000	0.000
100	B012	25.000	30.000	-5.000
100	B013	10.000	20.000	-10.000
100	B014	15.000	25.000	-10.000
100	B015	10.000	20.000	-10.000
	Max	25.000	30.000	10.000
	Average	16.250	20.000	-3.750
	Min	10.000	10.000	-20.000
	Std Dev	4.833	5.380	7.412



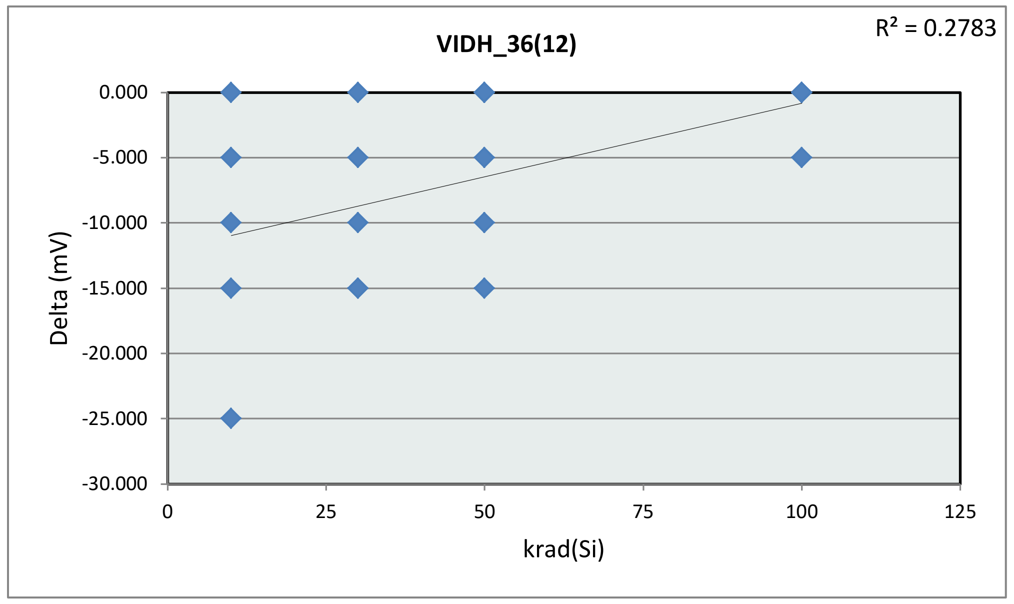
	DVTH_36(11)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	10.000	10.000	15.000	20.000
Average	20.000	17.000	19.000	24.000
Max	30.000	25.000	20.000	30.000
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
SN55LVCP22A-SP

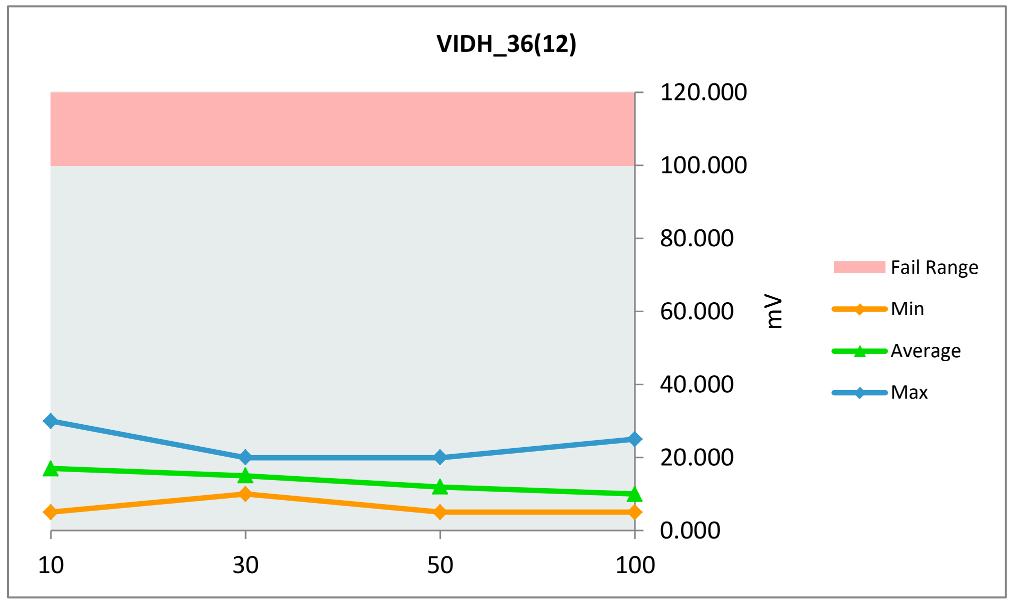
	VIDH_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	100	100
Min Limit		

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	5.000	30.000	-25.000
10	7	10.000	15.000	-5.000
10	8	5.000	5.000	0.000
10	9	5.000	15.000	-10.000
10	10	5.000	20.000	-15.000
30	6	5.000	20.000	-15.000
30	7	10.000	10.000	0.000
30	8	5.000	10.000	-5.000
30	9	5.000	15.000	-10.000
30	10	5.000	20.000	-15.000
50	6	5.000	20.000	-15.000
50	7	10.000	10.000	0.000
50	8	5.000	5.000	0.000
50	9	5.000	10.000	-5.000
50	10	5.000	15.000	-10.000
100	B011	20.000	25.000	-5.000
100	B012	10.000	10.000	0.000
100	B013	5.000	5.000	0.000
100	B014	5.000	5.000	0.000
100	B015	5.000	5.000	0.000
	Max	20.000	30.000	0.000
	Average	6.750	13.500	-6.750
	Min	5.000	5.000	-25.000
	Std Dev	3.726	7.273	7.304



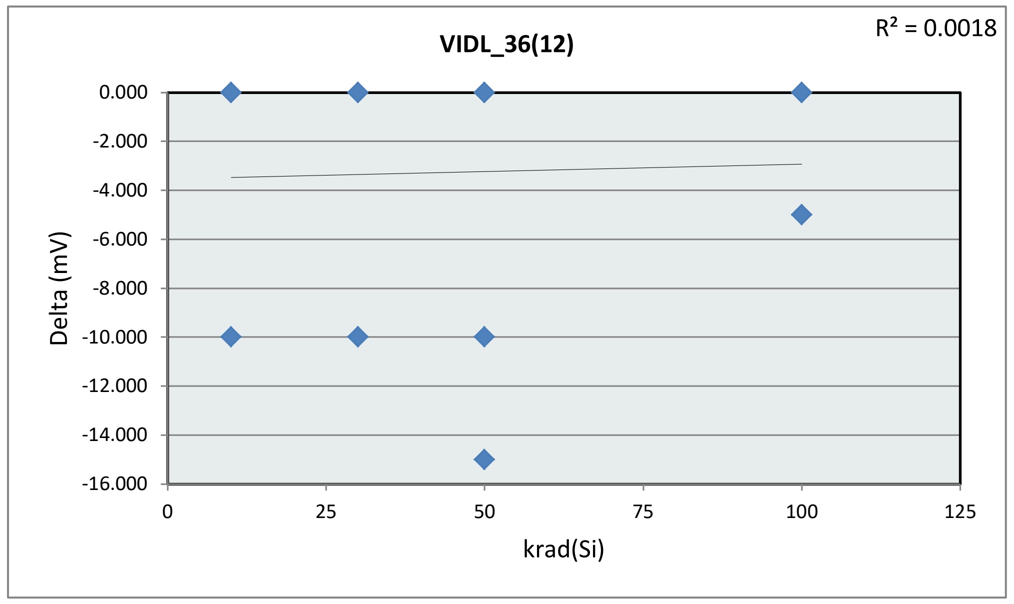
	VIDH_36(12)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	100	mV
Min Limit		mV

krad(Si)	10	30	50	100
LL				
Min	5.000	10.000	5.000	5.000
Average	17.000	15.000	12.000	10.000
Max	30.000	20.000	20.000	25.000
UL	100.000	100.000	100.000	100.000

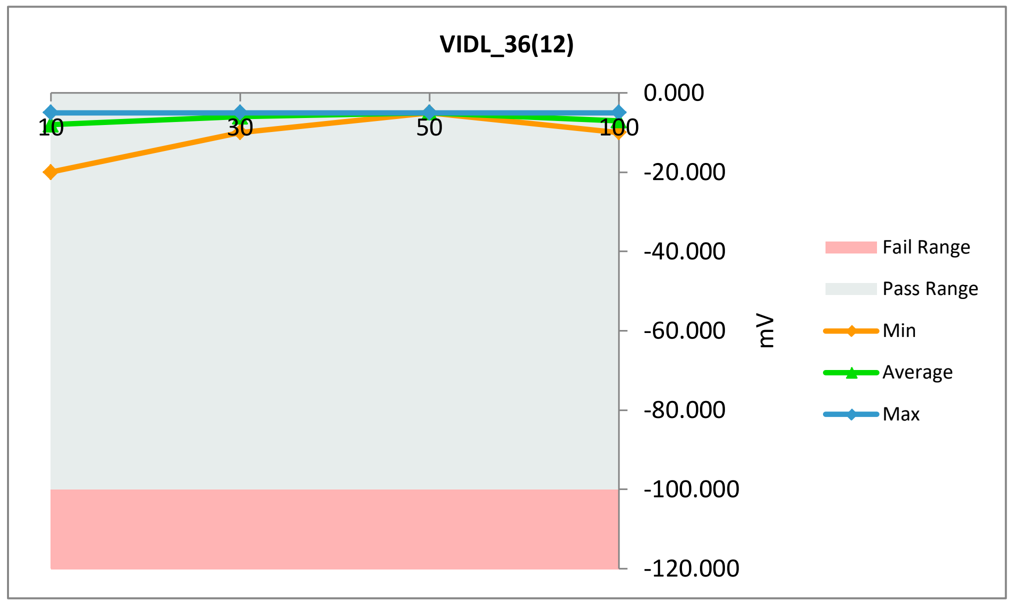


LDR UnBiased TID Report
SN55LVCP22A-SP

		VIDL_36(12)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		mV	mV	
Max Limit				
Min Limit		-100	-100	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	-15.000	-5.000	-10.000
10	7	-5.000	-5.000	0.000
10	8	-20.000	-20.000	0.000
10	9	-5.000	-5.000	0.000
10	10	-5.000	-5.000	0.000
30	6	-15.000	-5.000	-10.000
30	7	-5.000	-5.000	0.000
30	8	-20.000	-10.000	-10.000
30	9	-5.000	-5.000	0.000
30	10	-5.000	-5.000	0.000
50	6	-15.000	-5.000	-10.000
50	7	-5.000	-5.000	0.000
50	8	-20.000	-5.000	-15.000
50	9	-5.000	-5.000	0.000
50	10	-5.000	-5.000	0.000
100	B011	-5.000	-5.000	0.000
100	B012	-5.000	-5.000	0.000
100	B013	-5.000	-5.000	0.000
100	B014	-15.000	-10.000	-5.000
100	B015	-15.000	-10.000	-5.000
	Max	-5.000	-5.000	0.000
	Average	-9.750	-6.500	-3.250
	Min	-20.000	-20.000	-15.000
	Std Dev	6.172	3.663	4.940



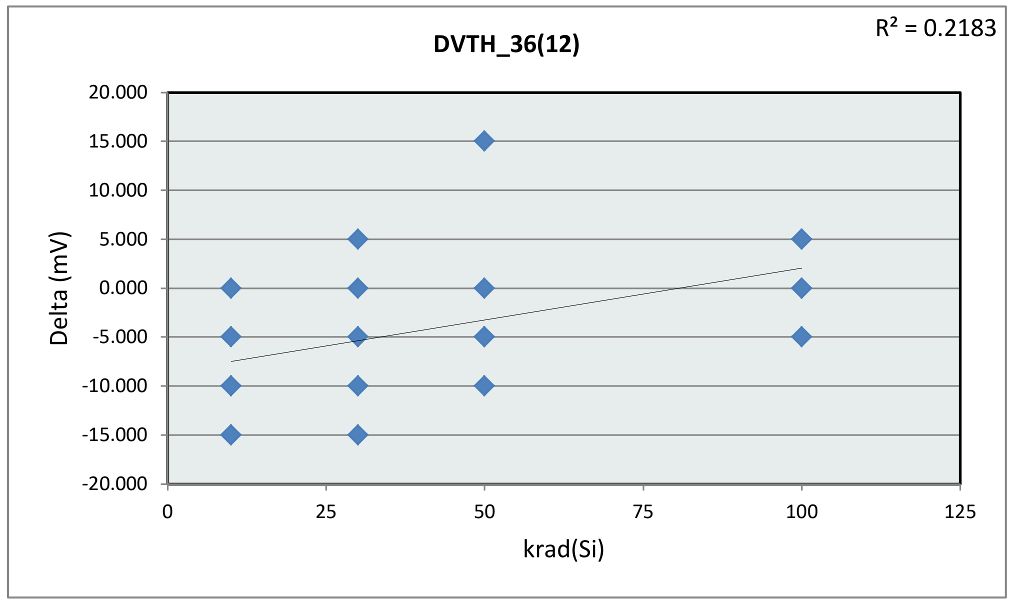
	VIDL_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit		mV		
Min Limit	-100	mV		
krad(Si)	10	30	50	100
LL	-100.000	-100.000	-100.000	-100.000
Min	-20.000	-10.000	-5.000	-10.000
Average	-8.000	-6.000	-5.000	-7.000
Max	-5.000	-5.000	-5.000	-5.000
UL				



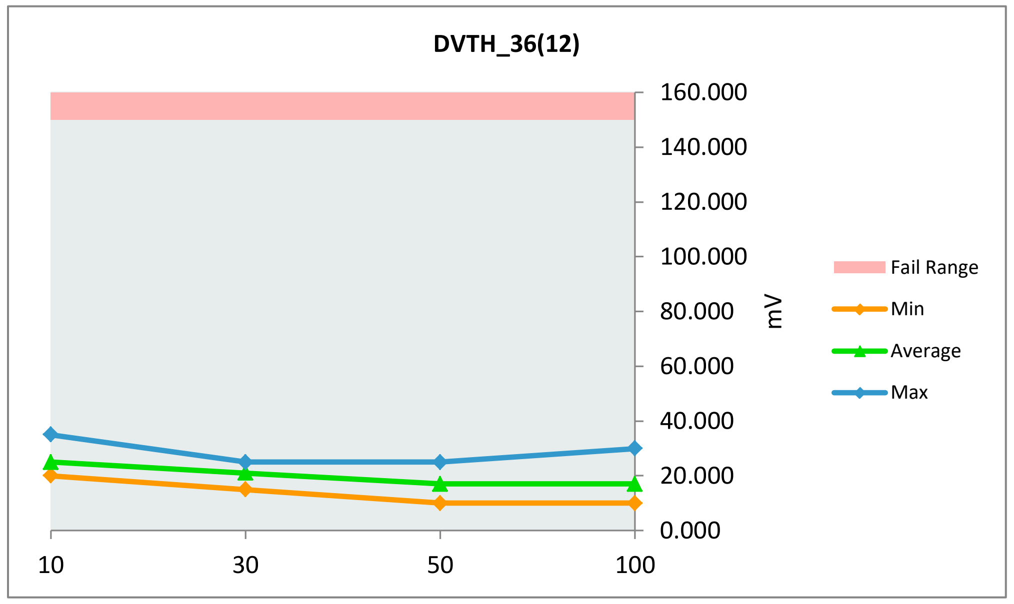
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVTH_36(12)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	150	150
Min Limit		

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	20.000	35.000	-15.000
10	7	15.000	20.000	-5.000
10	8	25.000	25.000	0.000
10	9	10.000	20.000	-10.000
10	10	10.000	25.000	-15.000
30	6	20.000	25.000	-5.000
30	7	15.000	15.000	0.000
30	8	25.000	20.000	5.000
30	9	10.000	20.000	-10.000
30	10	10.000	25.000	-15.000
50	6	20.000	25.000	-5.000
50	7	15.000	15.000	0.000
50	8	25.000	10.000	15.000
50	9	10.000	15.000	-5.000
50	10	10.000	20.000	-10.000
100	B011	25.000	30.000	-5.000
100	B012	15.000	15.000	0.000
100	B013	10.000	10.000	0.000
100	B014	20.000	15.000	5.000
100	B015	20.000	15.000	5.000
	Max	25.000	35.000	15.000
	Average	16.500	20.000	-3.500
	Min	10.000	10.000	-15.000
	Std Dev	5.871	6.489	7.797



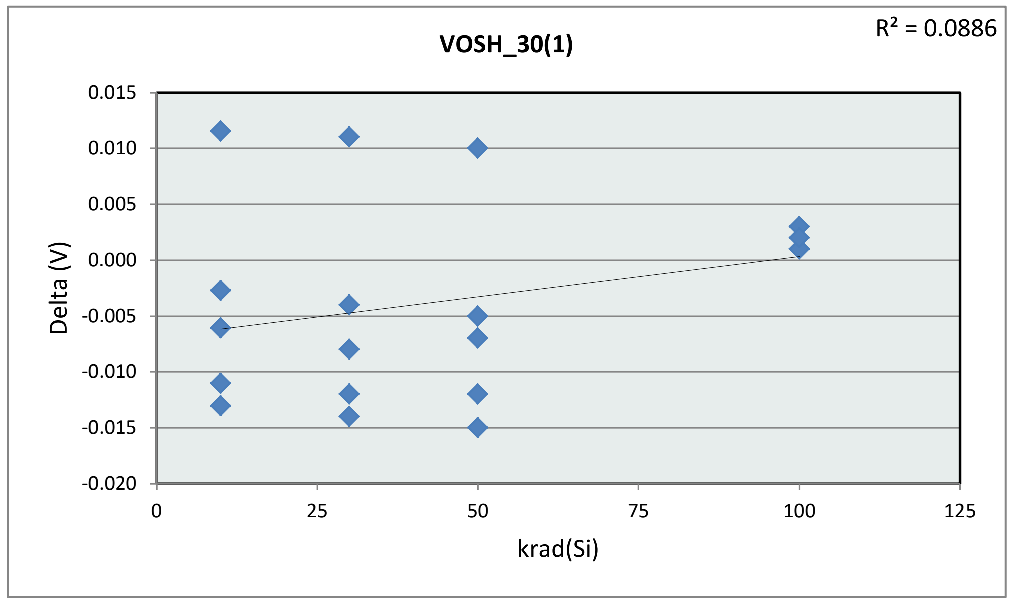
	DVTH_36(12)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	150	mV		
Min Limit		mV		
krad(Si)	10	30	50	100
LL				
Min	20.000	15.000	10.000	10.000
Average	25.000	21.000	17.000	17.000
Max	35.000	25.000	25.000	30.000
UL	150.000	150.000	150.000	150.000



LDR UnBiased TID Report
SN55LVCP22A-SP

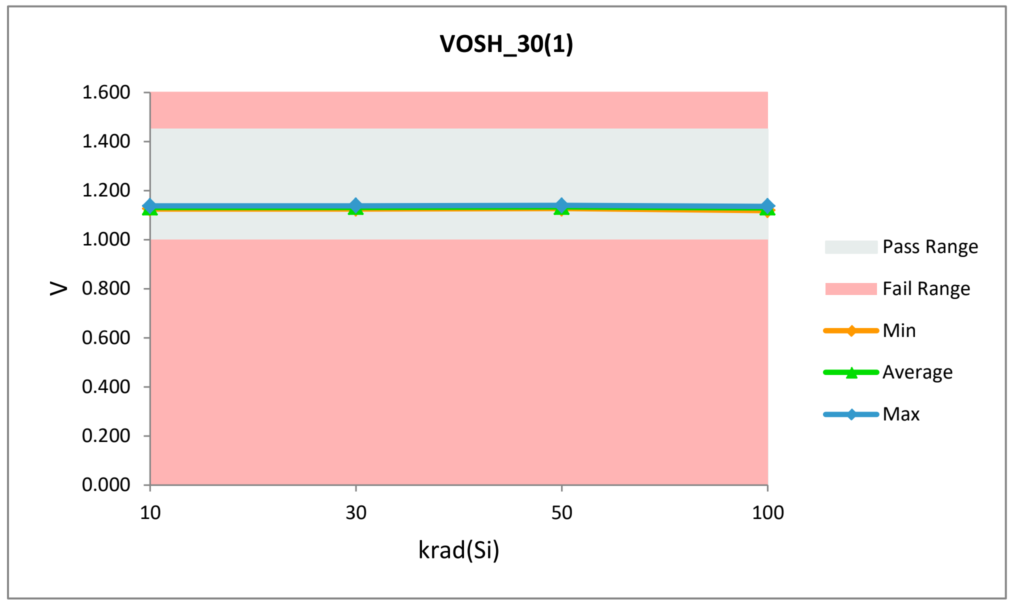
	VOSH_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	V	V
Max Limit	1.45	1.45
Min Limit	1	1

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.120	1.133	-0.013
10	7	1.122	1.133	-0.011
10	8	1.119	1.125	-0.006
10	9	1.134	1.137	-0.003
10	10	1.136	1.124	0.012
30	6	1.120	1.134	-0.014
30	7	1.122	1.134	-0.012
30	8	1.119	1.127	-0.008
30	9	1.134	1.138	-0.004
30	10	1.136	1.125	0.011
50	6	1.120	1.135	-0.015
50	7	1.122	1.134	-0.012
50	8	1.119	1.126	-0.007
50	9	1.134	1.139	-0.005
50	10	1.136	1.126	0.010
100	B011	1.133	1.132	0.001
100	B012	1.136	1.135	0.001
100	B013	1.134	1.131	0.003
100	B014	1.128	1.127	0.001
100	B015	1.120	1.118	0.002
	Max	1.136	1.139	0.012
	Average	1.127	1.131	-0.003
	Min	1.119	1.118	-0.015
	Std Dev	0.007	0.006	0.008



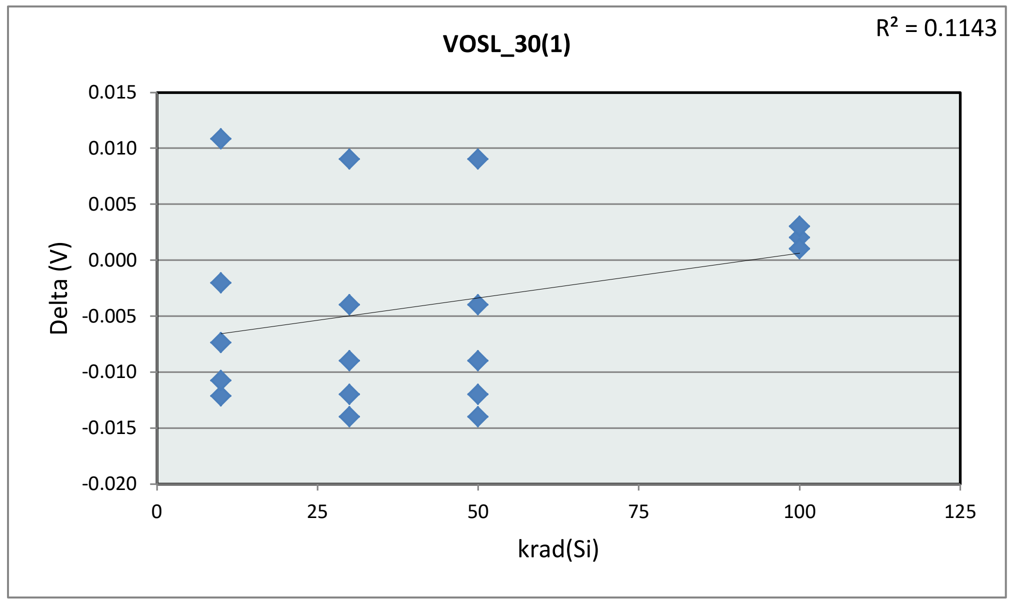
	VOSH_30(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	1.45	V
Min Limit	1	V

krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.124	1.125	1.126	1.118
Average	1.130	1.132	1.132	1.129
Max	1.137	1.138	1.139	1.135
UL	1.450	1.450	1.450	1.450

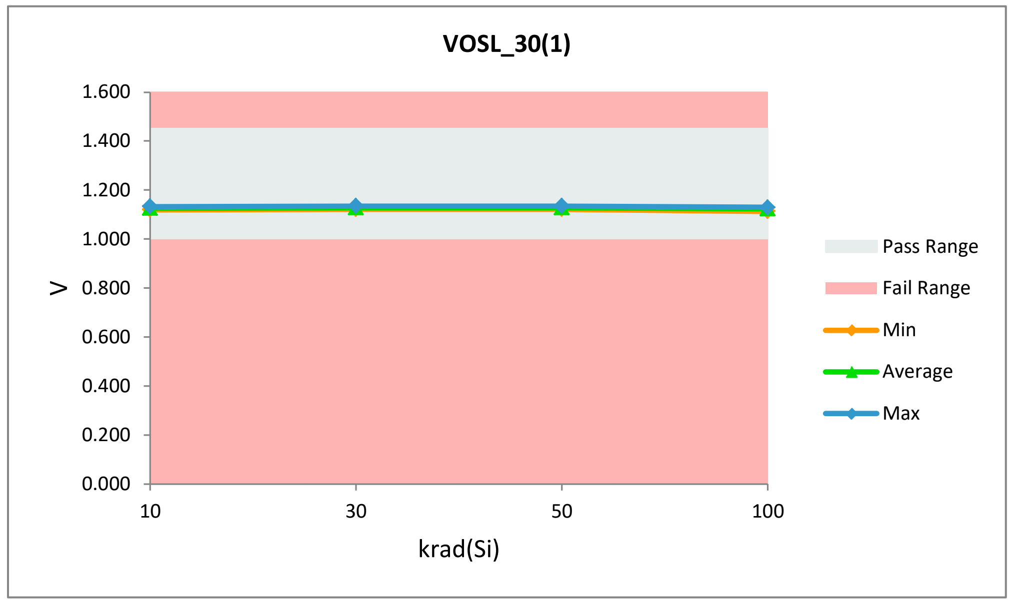


LDR UnBiased TID Report
SN55LVCP22A-SP

		VOSL_30(1)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.116	1.128	-0.012
10	7	1.118	1.129	-0.011
10	8	1.114	1.121	-0.007
10	9	1.131	1.133	-0.002
10	10	1.131	1.120	0.011
30	6	1.116	1.130	-0.014
30	7	1.118	1.130	-0.012
30	8	1.114	1.123	-0.009
30	9	1.131	1.135	-0.004
30	10	1.131	1.122	0.009
50	6	1.116	1.130	-0.014
50	7	1.118	1.130	-0.012
50	8	1.114	1.123	-0.009
50	9	1.131	1.135	-0.004
50	10	1.131	1.122	0.009
100	B011	1.130	1.129	0.001
100	B012	1.132	1.130	0.002
100	B013	1.130	1.127	0.003
100	B014	1.123	1.122	0.001
100	B015	1.116	1.113	0.003
	Max	1.132	1.135	0.011
	Average	1.123	1.127	-0.004
	Min	1.114	1.113	-0.014
	Std Dev	0.008	0.006	0.008



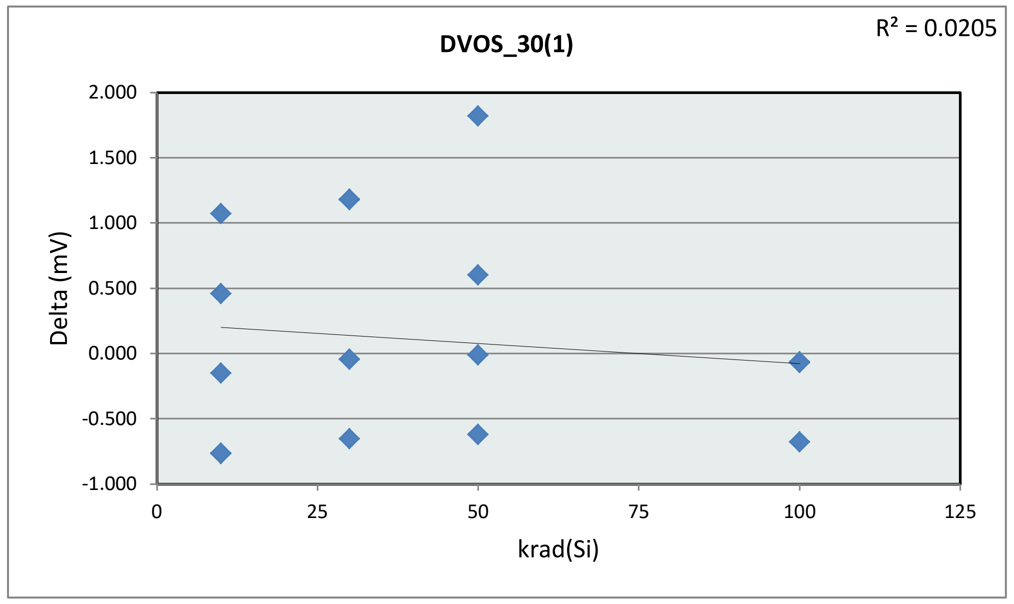
	VOSL_30(1)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.120	1.122	1.122	1.113
Average	1.126	1.128	1.128	1.124
Max	1.133	1.135	1.135	1.130
UL	1.450	1.450	1.450	1.450



LDR UnBiased TID Report
SN55LVCP22A-SP

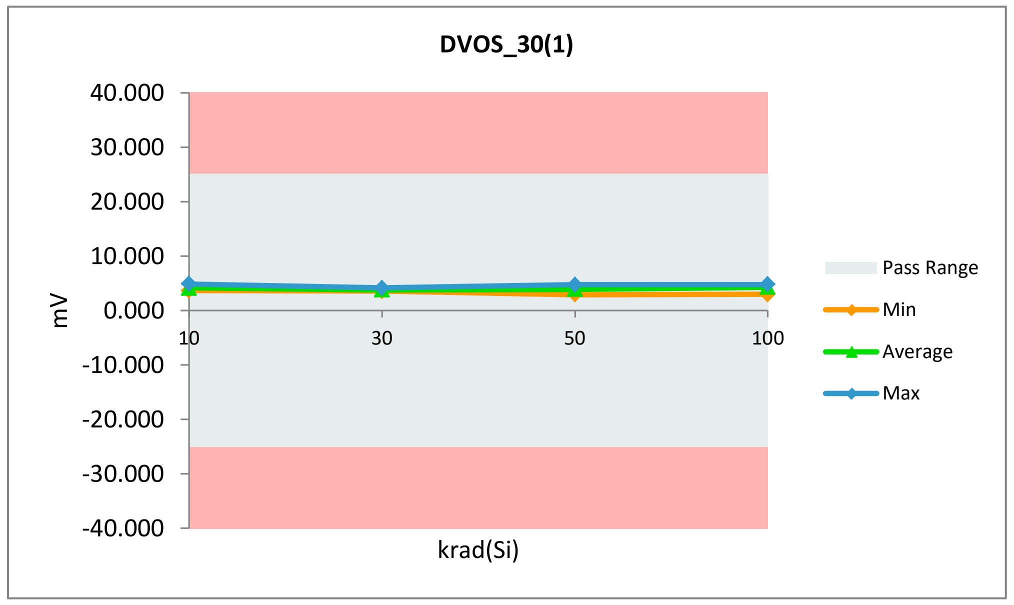
	DVOS_30(1)	
Test Site	SLL LAB	SLL LAB
Tester	IMP	IMP
Test Number	I2107203	I2107203
Unit	mV	mV
Max Limit	25	25
Min Limit	-25	-25

krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	4.139	4.909	-0.770
10	7	3.532	4.295	-0.763
10	8	4.751	3.682	1.069
10	9	3.531	3.682	-0.151
10	10	4.753	4.295	0.458
30	6	4.139	4.184	-0.045
30	7	3.532	4.184	-0.652
30	8	4.751	3.574	1.177
30	9	3.531	3.574	-0.043
30	10	4.753	3.573	1.180
50	6	4.139	4.762	-0.623
50	7	3.532	4.152	-0.620
50	8	4.751	2.931	1.820
50	9	3.531	3.542	-0.011
50	10	4.753	4.152	0.601
100	B011	2.921	2.988	-0.067
100	B012	4.141	4.209	-0.068
100	B013	4.752	4.820	-0.068
100	B014	4.751	4.820	-0.069
100	B015	4.139	4.819	-0.680
	Max	4.753	4.909	1.820
	Average	4.141	4.057	0.084
	Min	2.921	2.931	-0.770
	Std Dev	0.594	0.599	0.745



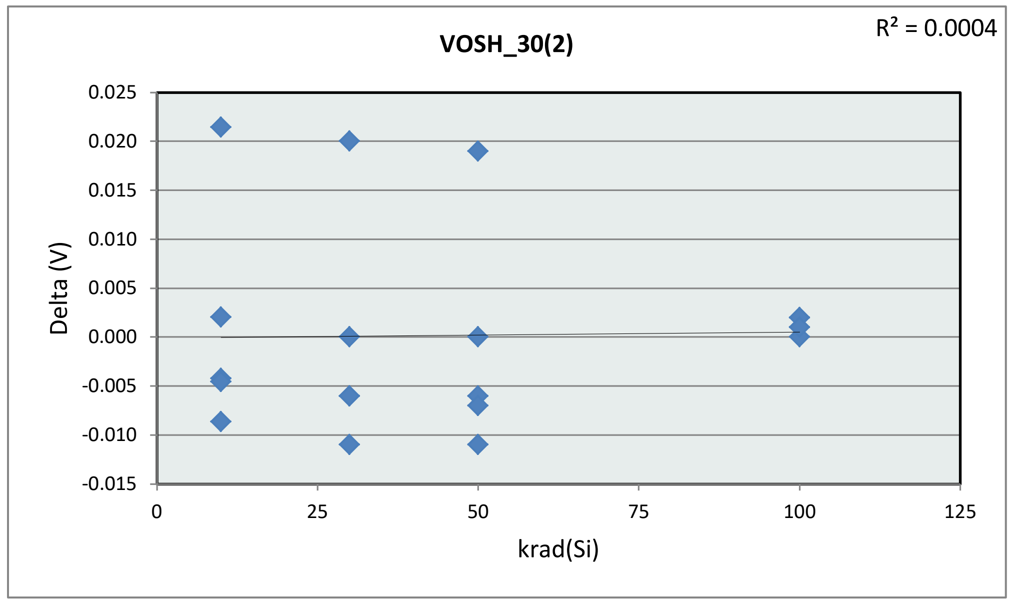
	DVOS_30(1)	
Test Site	SLL LAB	
Tester	IMP	
Test Number	I2107203	
Max Limit	25	mV
Min Limit	-25	mV

krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.682	3.573	2.931	2.988
Average	4.172	3.818	3.908	4.331
Max	4.909	4.184	4.762	4.820
UL	25.000	25.000	25.000	25.000

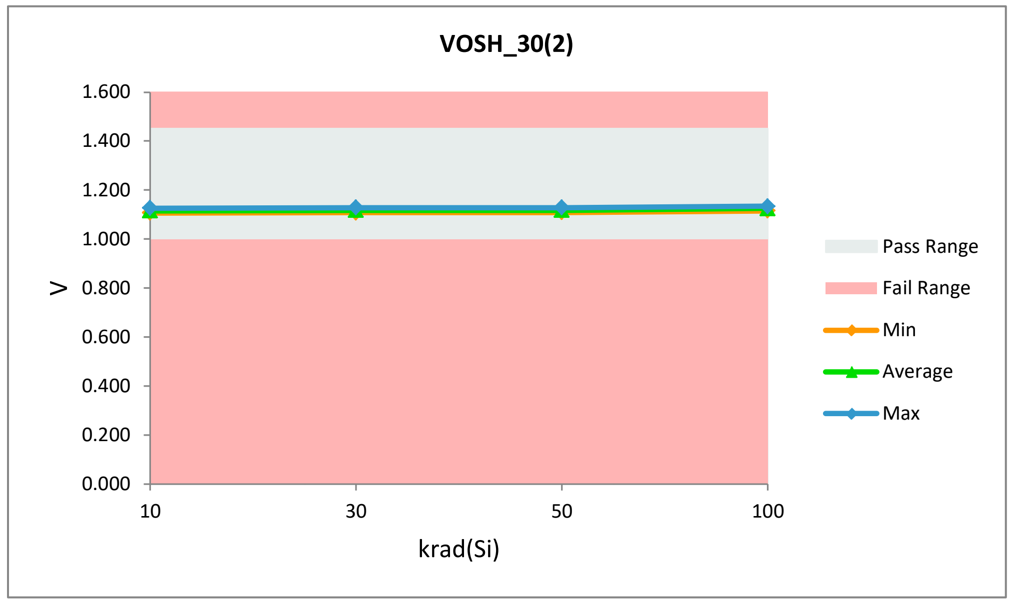


LDR UnBiased TID Report
SN55LVCP22A-SP

		VOSH_30(2)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.116	1.114	0.002
10	7	1.128	1.107	0.021
10	8	1.122	1.126	-0.004
10	9	1.109	1.118	-0.009
10	10	1.110	1.115	-0.005
30	6	1.116	1.116	0.000
30	7	1.128	1.108	0.020
30	8	1.122	1.128	-0.006
30	9	1.109	1.120	-0.011
30	10	1.110	1.116	-0.006
50	6	1.116	1.116	0.000
50	7	1.128	1.109	0.019
50	8	1.122	1.128	-0.006
50	9	1.109	1.120	-0.011
50	10	1.110	1.117	-0.007
100	B011	1.131	1.130	0.001
100	B012	1.117	1.115	0.002
100	B013	1.136	1.134	0.002
100	B014	1.132	1.132	0.000
100	B015	1.116	1.115	0.001
	Max	1.136	1.134	0.021
	Average	1.119	1.119	0.000
	Min	1.109	1.107	-0.011
	Std Dev	0.009	0.008	0.010

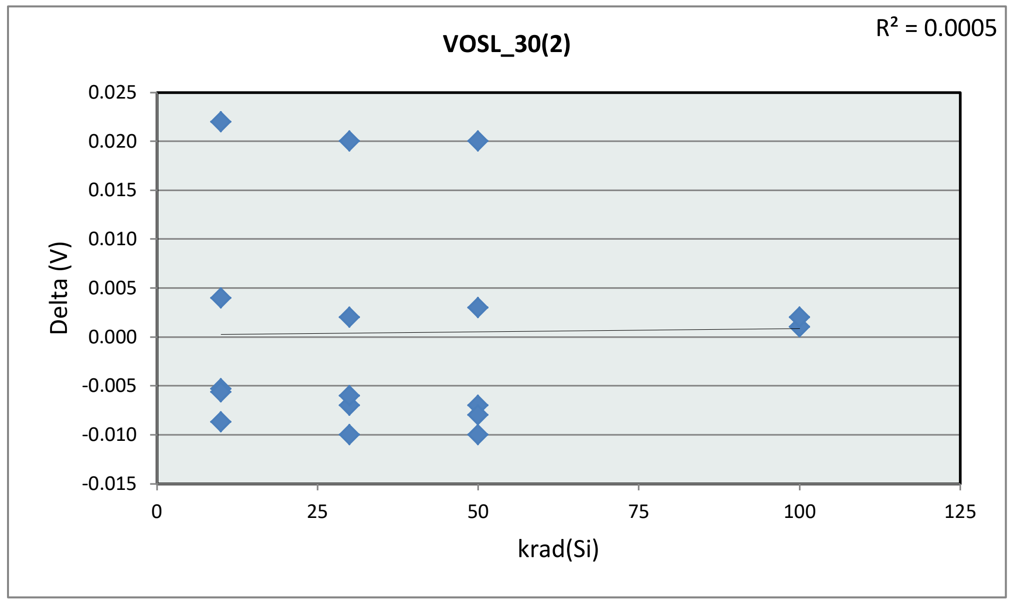


	VOSH_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.107	1.108	1.109	1.115
Average	1.116	1.118	1.118	1.125
Max	1.126	1.128	1.128	1.134
UL	1.450	1.450	1.450	1.450

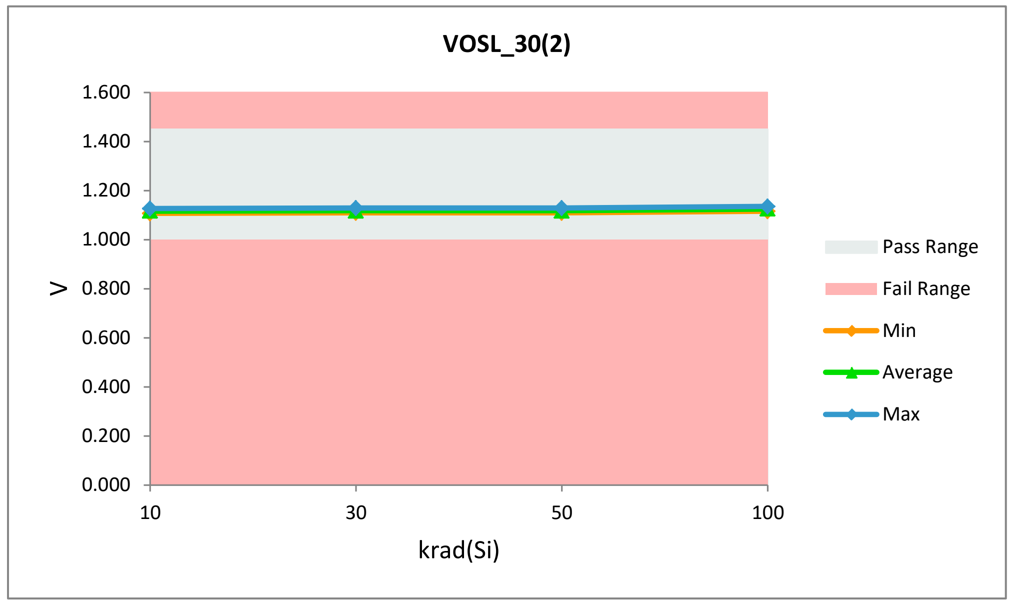


LDR UnBiased TID Report
SN55LVCP22A-SP

		VOSL_30(2)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.118	1.114	0.004
10	7	1.128	1.106	0.022
10	8	1.121	1.126	-0.005
10	9	1.109	1.118	-0.009
10	10	1.109	1.115	-0.006
30	6	1.118	1.116	0.002
30	7	1.128	1.108	0.020
30	8	1.121	1.128	-0.007
30	9	1.109	1.119	-0.010
30	10	1.109	1.115	-0.006
50	6	1.118	1.115	0.003
50	7	1.128	1.108	0.020
50	8	1.121	1.128	-0.007
50	9	1.109	1.119	-0.010
50	10	1.109	1.117	-0.008
100	B011	1.131	1.130	0.001
100	B012	1.117	1.115	0.002
100	B013	1.135	1.134	0.001
100	B014	1.132	1.131	0.001
100	B015	1.118	1.116	0.002
	Max	1.135	1.134	0.022
	Average	1.119	1.119	0.001
	Min	1.109	1.106	-0.010
	Std Dev	0.009	0.008	0.010



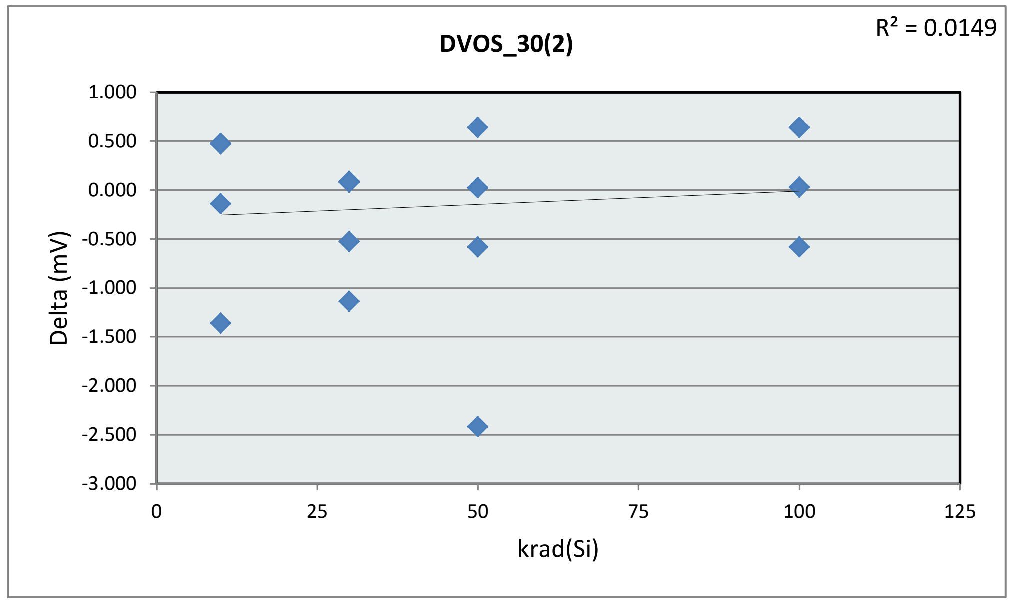
	VOSL_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.106	1.108	1.108	1.115
Average	1.116	1.117	1.117	1.125
Max	1.126	1.128	1.128	1.134
UL	1.450	1.450	1.450	1.450



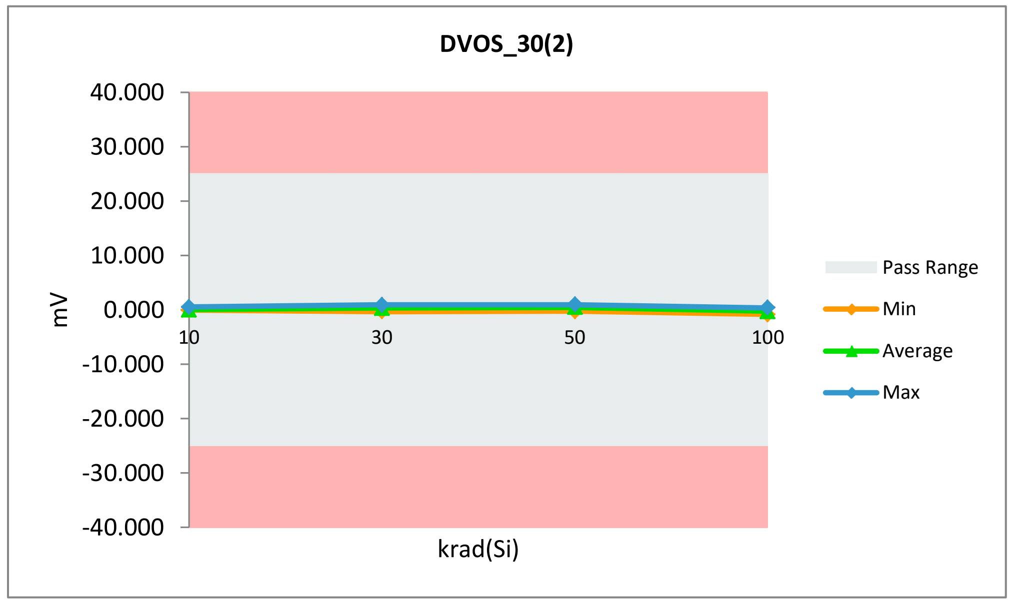
LDR UnBiased TID Report
SN55LVCP22A-SP

	DVOS_30(2)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	mV	mV	
Max Limit	25	25	
Min Limit	-25	-25	

krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	-1.425	-0.063	-1.362
10	7	0.412	0.551	-0.139
10	8	0.409	-0.062	0.471
10	9	0.409	-0.063	0.472
10	10	0.410	-0.063	0.473
30	6	-1.425	-0.285	-1.140
30	7	0.412	0.326	0.086
30	8	0.409	0.332	0.077
30	9	0.409	0.328	0.082
30	10	0.410	0.936	-0.525
50	6	-1.425	0.996	-2.421
50	7	0.412	0.996	-0.583
50	8	0.409	0.389	0.020
50	9	0.409	0.386	0.024
50	10	0.410	-0.227	0.637
100	B011	0.409	-0.231	0.640
100	B012	-0.201	-0.229	0.028
100	B013	0.413	-0.226	0.639
100	B014	0.410	0.382	0.028
100	B015	-1.425	-0.842	-0.583
	Max	0.413	0.996	0.640
	Average	0.013	0.166	-0.154
	Min	-1.425	-0.842	-2.421
	Std Dev	0.750	0.481	0.776



	DVOS_30(2)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	-0.063	-0.285	-0.227	-0.842
Average	0.060	0.327	0.508	-0.229
Max	0.551	0.936	0.996	0.382
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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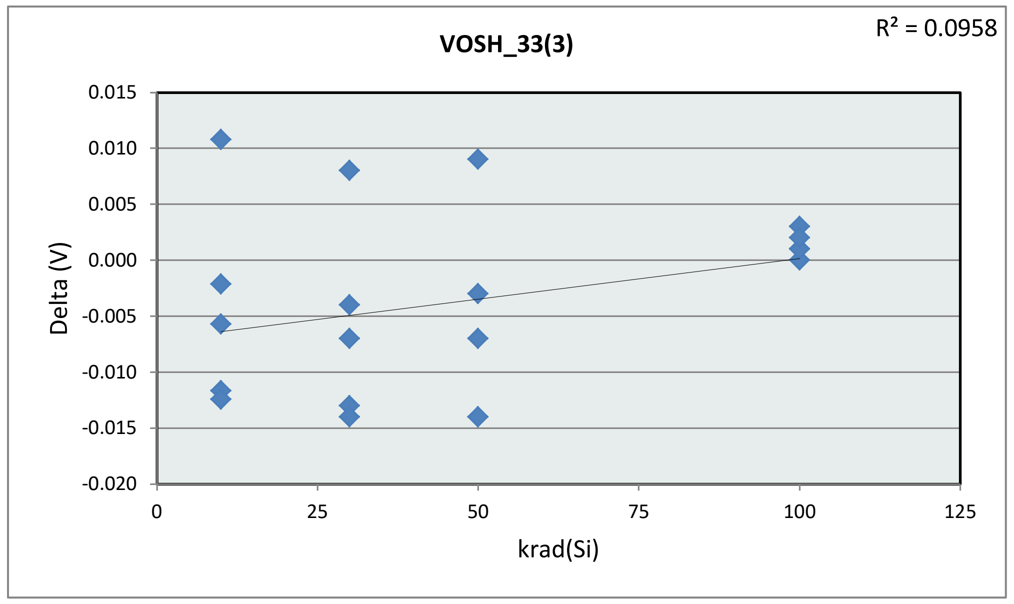
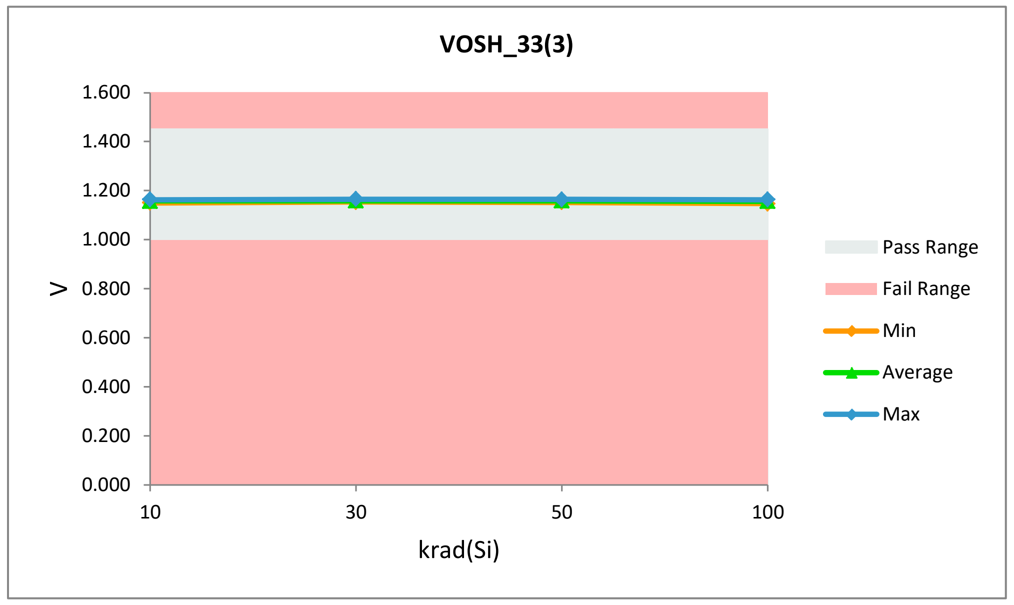
		VOSH_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.149	1.161	-0.012
10	7	1.147	1.159	-0.012
10	8	1.147	1.153	-0.006
10	9	1.161	1.163	-0.002
10	10	1.161	1.150	0.011
30	6	1.149	1.162	-0.013
30	7	1.147	1.161	-0.014
30	8	1.147	1.154	-0.007
30	9	1.161	1.165	-0.004
30	10	1.161	1.153	0.008
50	6	1.149	1.163	-0.014
50	7	1.147	1.161	-0.014
50	8	1.147	1.154	-0.007
50	9	1.161	1.164	-0.003
50	10	1.161	1.152	0.009
100	B011	1.159	1.159	0.000
100	B012	1.164	1.163	0.001
100	B013	1.162	1.159	0.003
100	B014	1.155	1.154	0.001
100	B015	1.149	1.147	0.002
	Max	1.164	1.165	0.011
	Average	1.154	1.158	-0.004
	Min	1.147	1.147	-0.014
	Std Dev	0.007	0.005	0.008



	VOSH_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.150	1.153	1.152	1.147
Average	1.157	1.159	1.159	1.156
Max	1.163	1.165	1.164	1.163
UL	1.450	1.450	1.450	1.450



LDR UnBiased TID Report
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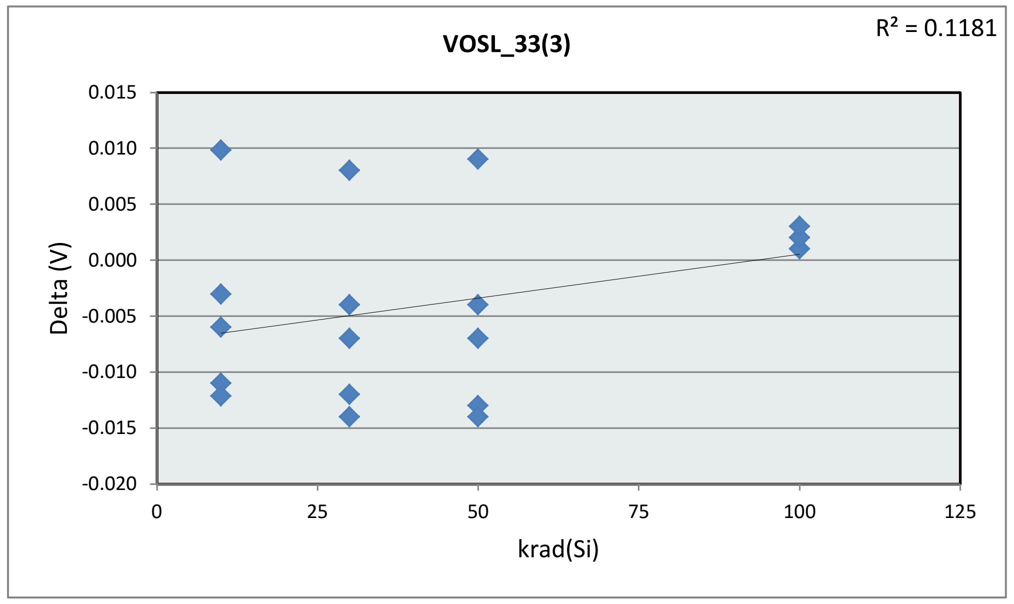
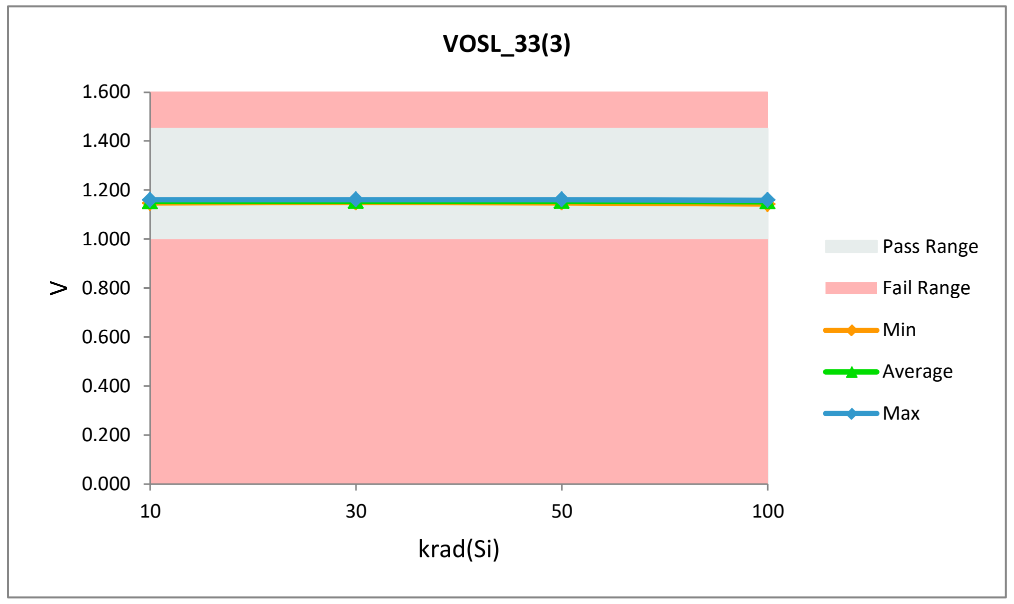
		VOSL_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	1.146	1.157	-0.011
10	7	1.143	1.155	-0.012
10	8	1.143	1.149	-0.006
10	9	1.157	1.160	-0.003
10	10	1.157	1.147	0.010
30	6	1.146	1.158	-0.012
30	7	1.143	1.157	-0.014
30	8	1.143	1.150	-0.007
30	9	1.157	1.161	-0.004
30	10	1.157	1.149	0.008
50	6	1.146	1.159	-0.013
50	7	1.143	1.157	-0.014
50	8	1.143	1.150	-0.007
50	9	1.157	1.161	-0.004
50	10	1.157	1.148	0.009
100	B011	1.157	1.156	0.001
100	B012	1.160	1.159	0.001
100	B013	1.157	1.155	0.002
100	B014	1.151	1.149	0.002
100	B015	1.146	1.143	0.003
	Max	1.160	1.161	0.010
	Average	1.150	1.154	-0.004
	Min	1.143	1.143	-0.014
	Std Dev	0.007	0.005	0.008

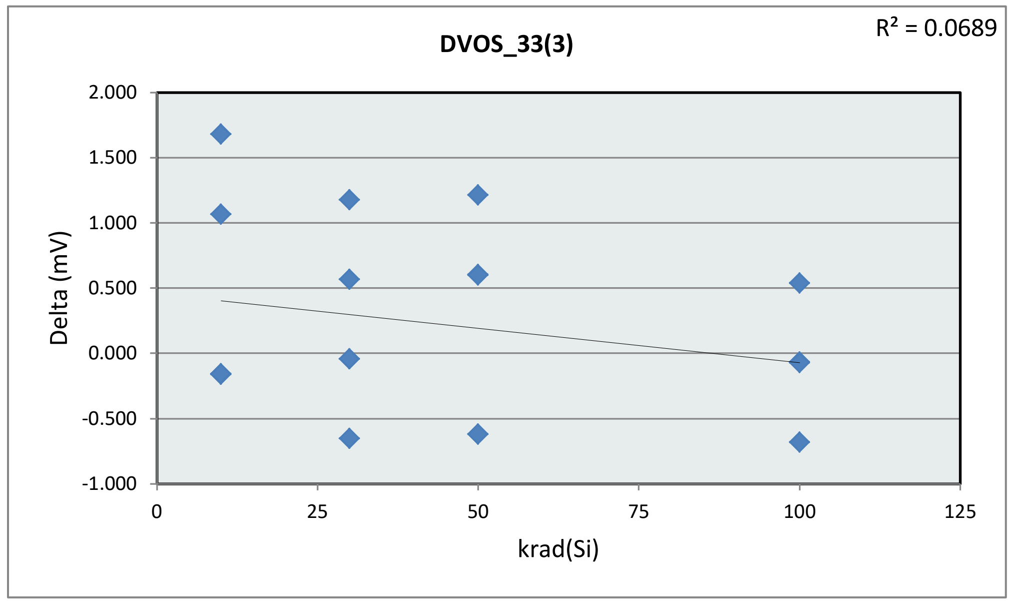


	VOSL_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.147	1.149	1.148	1.143
Average	1.154	1.155	1.155	1.152
Max	1.160	1.161	1.161	1.159
UL	1.450	1.450	1.450	1.450

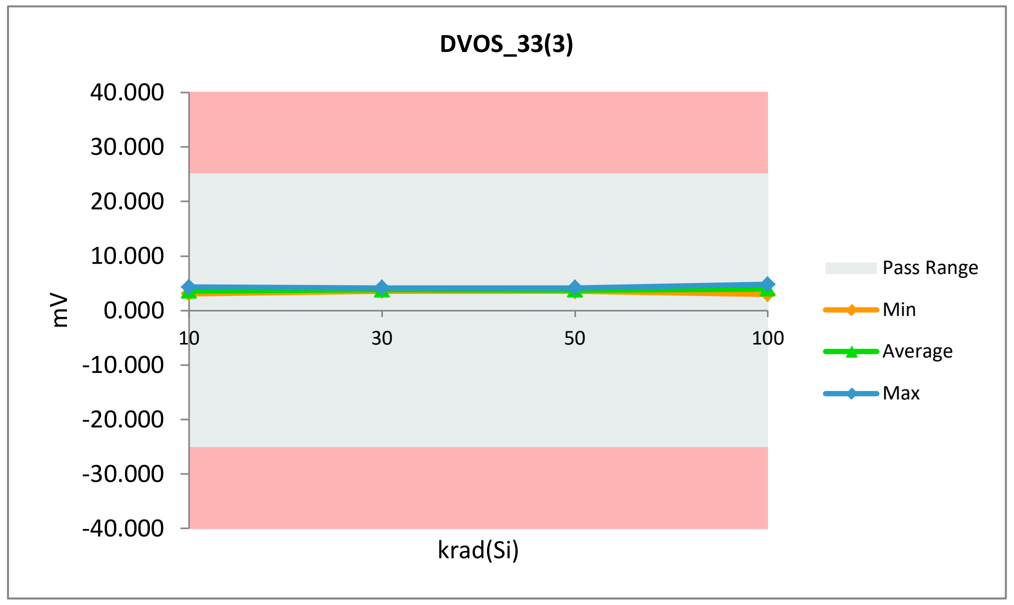


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVOS_33(3)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbia	Delta
10	6	3.524	3.682	-0.158
10	7	4.135	4.295	-0.160
10	8	3.524	3.682	-0.158
10	9	4.134	3.068	1.066
10	10	4.746	3.068	1.678
30	6	3.524	4.179	-0.655
30	7	4.135	4.179	-0.044
30	8	3.524	3.568	-0.044
30	9	4.134	3.569	0.565
30	10	4.746	3.569	1.177
50	6	3.524	4.146	-0.622
50	7	4.135	3.534	0.601
50	8	3.524	4.144	-0.620
50	9	4.134	3.535	0.599
50	10	4.746	3.535	1.211
100	B011	2.914	2.984	-0.070
100	B012	4.135	4.205	-0.070
100	B013	4.744	4.205	0.539
100	B014	4.134	4.816	-0.682
100	B015	3.524	3.595	-0.071
	Max	4.746	4.816	1.678
	Average	3.982	3.778	0.204
	Min	2.914	2.984	-0.682
	Std Dev	0.519	0.476	0.691



	DVOS_33(3)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	3.068	3.568	3.534	2.984
Average	3.559	3.813	3.779	3.961
Max	4.295	4.179	4.146	4.816
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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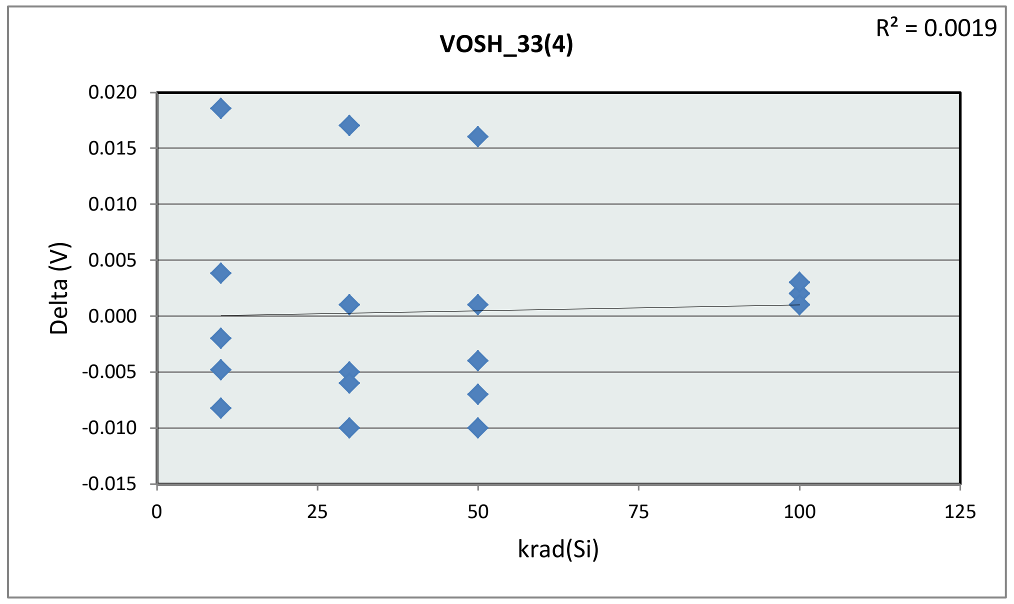
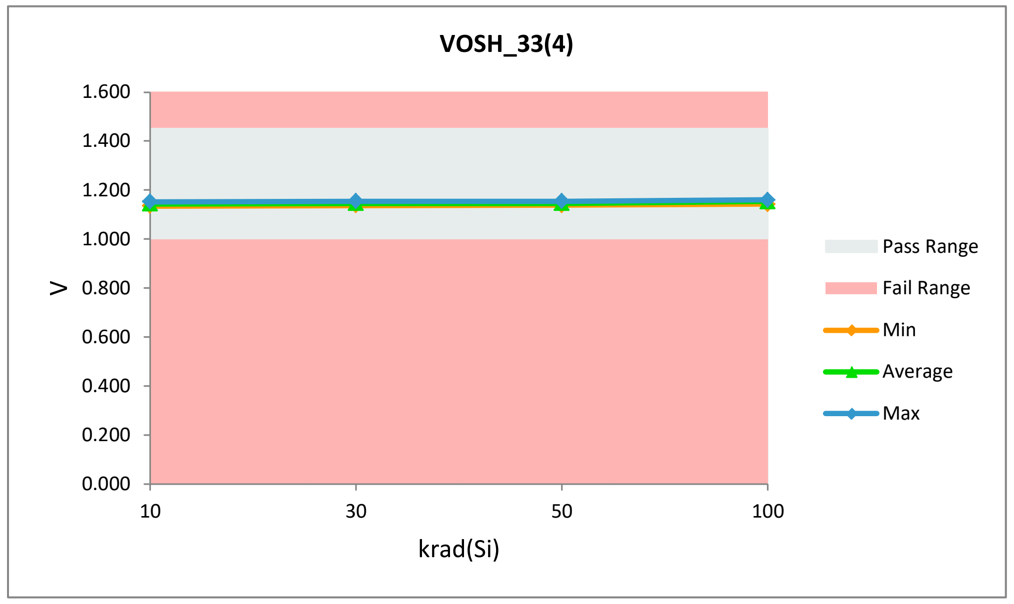
		VOSH_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.146	1.142	0.004
10	7	1.154	1.135	0.019
10	8	1.150	1.152	-0.002
10	9	1.137	1.145	-0.008
10	10	1.138	1.143	-0.005
30	6	1.146	1.145	0.001
30	7	1.154	1.137	0.017
30	8	1.150	1.155	-0.005
30	9	1.137	1.147	-0.010
30	10	1.138	1.144	-0.006
50	6	1.146	1.145	0.001
50	7	1.154	1.138	0.016
50	8	1.150	1.154	-0.004
50	9	1.137	1.147	-0.010
50	10	1.138	1.145	-0.007
100	B011	1.160	1.159	0.001
100	B012	1.146	1.144	0.002
100	B013	1.162	1.160	0.002
100	B014	1.160	1.159	0.001
100	B015	1.146	1.143	0.003
	Max	1.162	1.160	0.019
	Average	1.147	1.147	0.000
	Min	1.137	1.135	-0.010
	Std Dev	0.008	0.007	0.008



	VOSH_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.135	1.137	1.138	1.143
Average	1.144	1.146	1.146	1.153
Max	1.152	1.155	1.154	1.160
UL	1.450	1.450	1.450	1.450



LDR UnBiased TID Report
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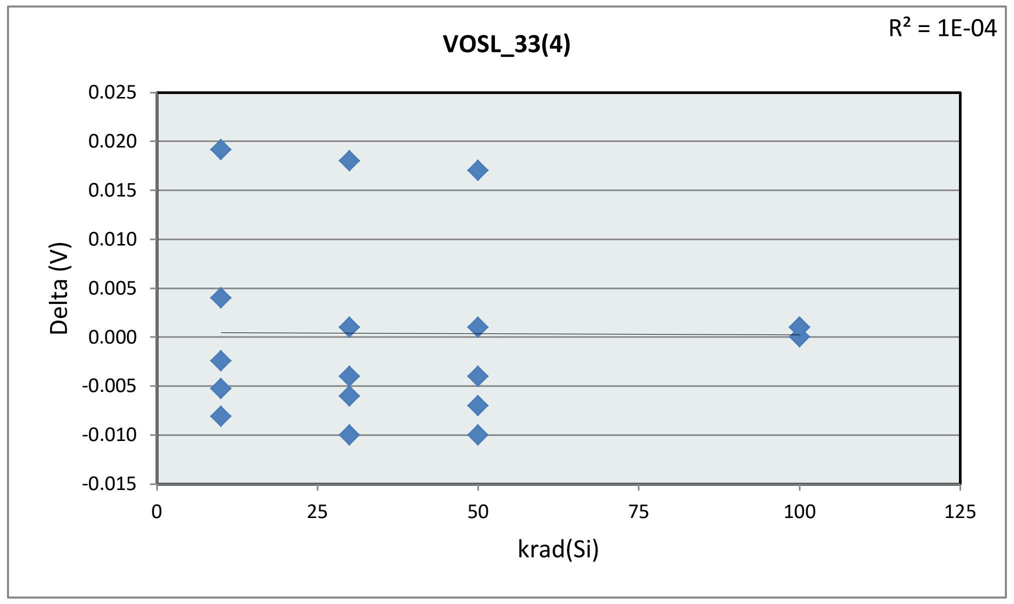
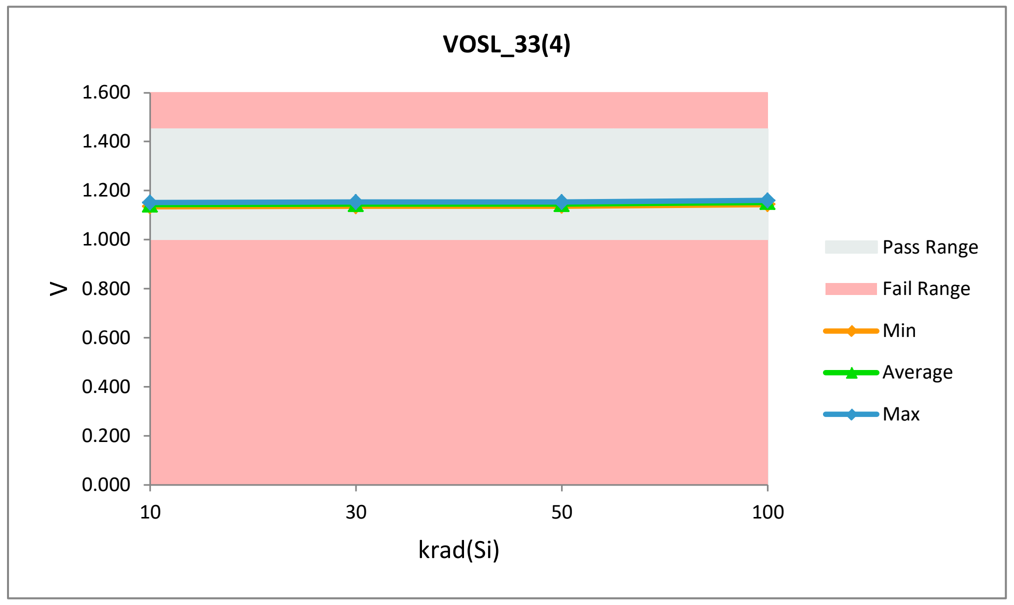
		VOSL_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	R Pre Test (unbias	R Post Test Unbias	Delta
10	6	1.145	1.141	0.004
10	7	1.154	1.135	0.019
10	8	1.149	1.151	-0.002
10	9	1.136	1.144	-0.008
10	10	1.137	1.142	-0.005
30	6	1.145	1.144	0.001
30	7	1.154	1.136	0.018
30	8	1.149	1.153	-0.004
30	9	1.136	1.146	-0.010
30	10	1.137	1.143	-0.006
50	6	1.145	1.144	0.001
50	7	1.154	1.137	0.017
50	8	1.149	1.153	-0.004
50	9	1.136	1.146	-0.010
50	10	1.137	1.144	-0.007
100	B011	1.158	1.158	0.000
100	B012	1.145	1.144	0.001
100	B013	1.161	1.160	0.001
100	B014	1.159	1.158	0.001
100	B015	1.145	1.144	0.001
	Max	1.161	1.160	0.019
	Average	1.147	1.146	0.000
	Min	1.136	1.135	-0.010
	Std Dev	0.008	0.007	0.009



	VOSL_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.135	1.136	1.137	1.144
Average	1.143	1.144	1.145	1.153
Max	1.151	1.153	1.153	1.160
UL	1.450	1.450	1.450	1.450



LDR UnBiased TID Report
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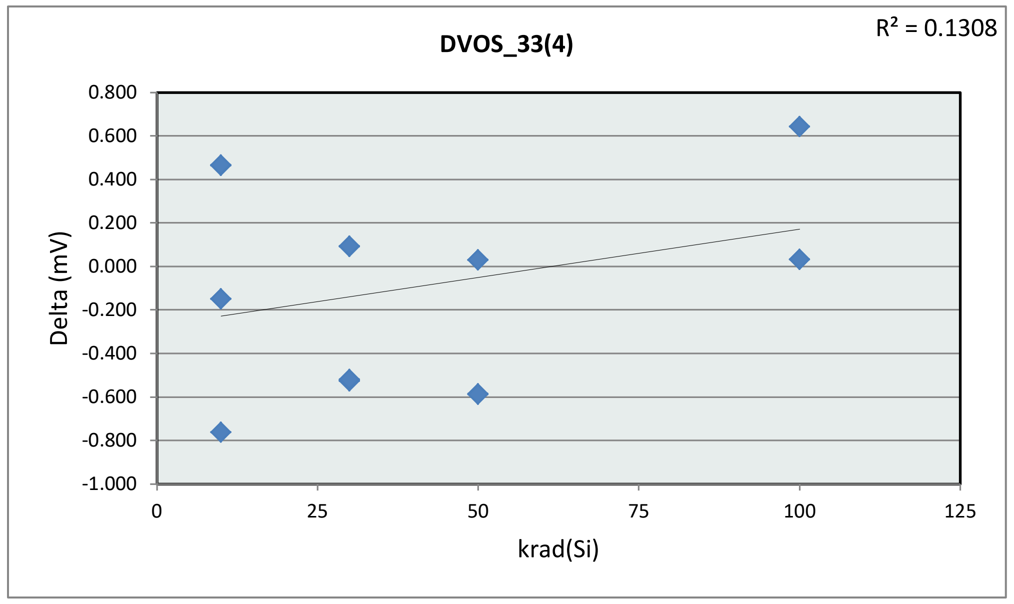
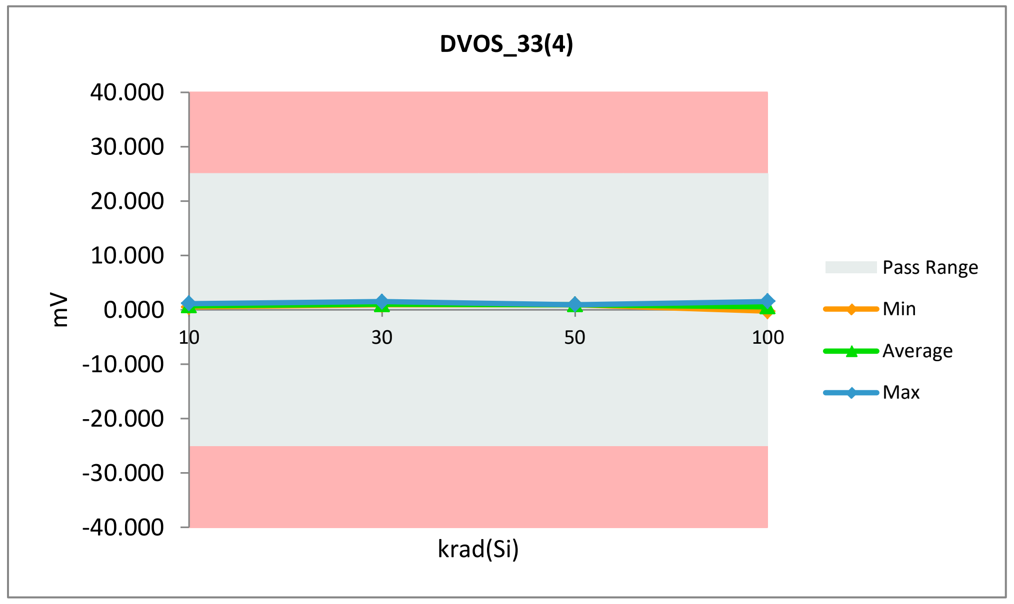
		DVOS_33(4)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.397	1.161	-0.764
10	7	0.396	0.547	-0.151
10	8	1.009	0.546	0.463
10	9	1.011	1.160	-0.149
10	10	1.012	0.547	0.465
30	6	0.397	0.922	-0.525
30	7	0.396	0.923	-0.526
30	8	1.009	1.530	-0.521
30	9	1.011	0.921	0.090
30	10	1.012	0.920	0.092
50	6	0.397	0.984	-0.587
50	7	0.396	0.985	-0.588
50	8	1.009	0.981	0.028
50	9	1.011	0.983	0.028
50	10	1.012	0.982	0.030
100	B011	1.619	1.588	0.031
100	B012	0.399	0.369	0.031
100	B013	1.008	0.366	0.642
100	B014	1.008	0.977	0.031
100	B015	0.397	-0.244	0.641
	Max	1.619	1.588	0.642
	Average	0.795	0.857	-0.062
	Min	0.396	-0.244	-0.764
	Std Dev	0.359	0.414	0.419



	DVOS_33(4)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.546	0.920	0.981	-0.244
Average	0.792	1.043	0.983	0.611
Max	1.161	1.530	0.985	1.588
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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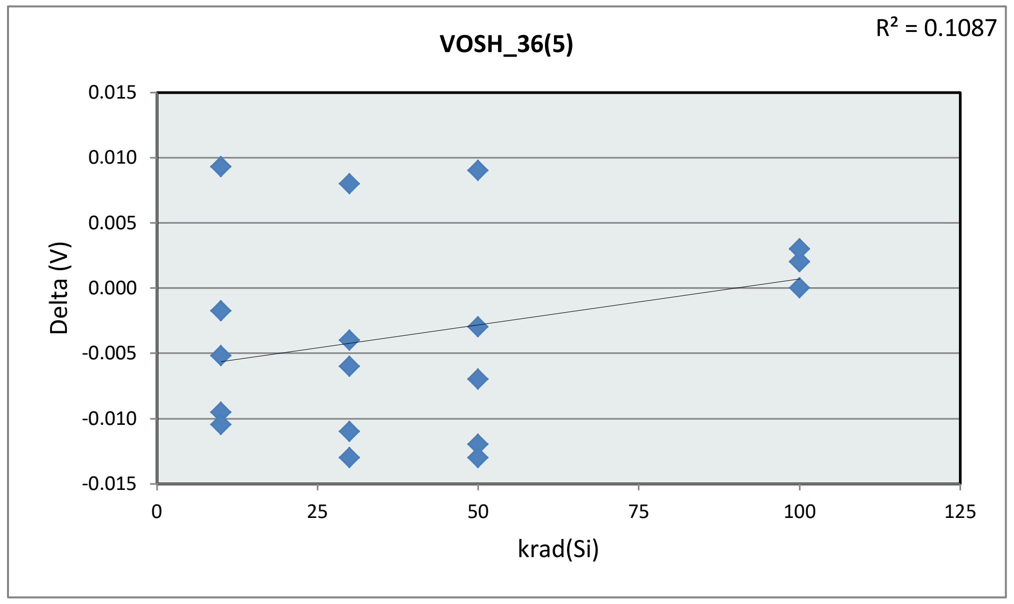
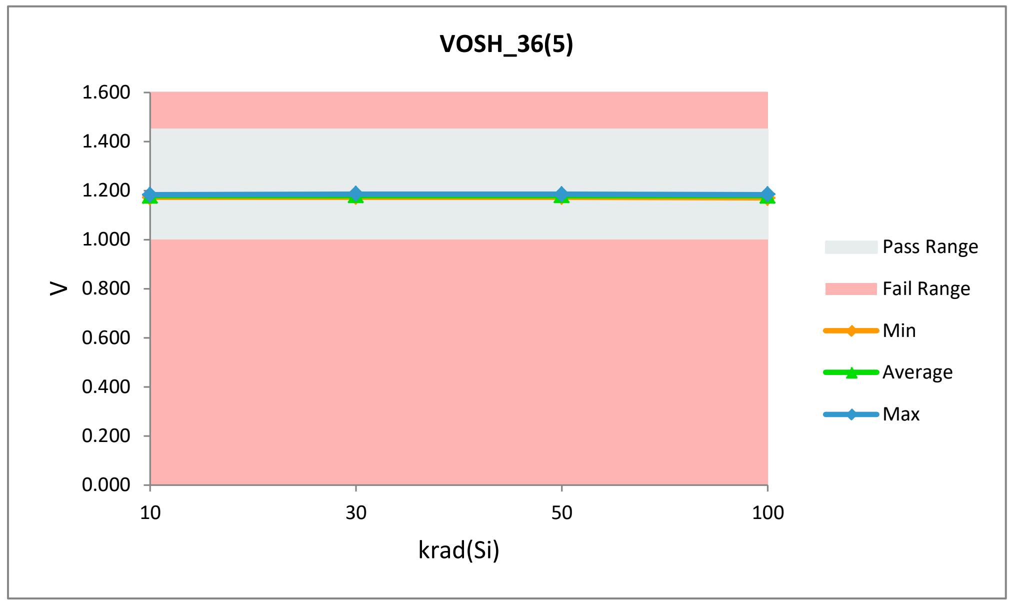
		VOSH_36(5)		
Test Site		SLL LAB	SLL LAB	
Tester		IMP	IMP	
Test Number		I2107203	I2107203	
Unit		V	V	
Max Limit		1.45	1.45	
Min Limit		1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.172	1.182	-0.010
10	7	1.168	1.178	-0.010
10	8	1.169	1.174	-0.005
10	9	1.181	1.183	-0.002
10	10	1.181	1.172	0.009
30	6	1.172	1.183	-0.011
30	7	1.168	1.181	-0.013
30	8	1.169	1.175	-0.006
30	9	1.181	1.185	-0.004
30	10	1.181	1.173	0.008
50	6	1.172	1.184	-0.012
50	7	1.168	1.181	-0.013
50	8	1.169	1.176	-0.007
50	9	1.181	1.184	-0.003
50	10	1.181	1.172	0.009
100	B011	1.180	1.180	0.000
100	B012	1.186	1.183	0.003
100	B013	1.183	1.181	0.002
100	B014	1.177	1.175	0.002
100	B015	1.172	1.169	0.003
	Max	1.186	1.185	0.009
	Average	1.176	1.179	-0.003
	Min	1.168	1.169	-0.013
	Std Dev	0.006	0.005	0.007



	VOSH_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.172	1.173	1.172	1.169
Average	1.178	1.179	1.179	1.178
Max	1.183	1.185	1.184	1.183
UL	1.450	1.450	1.450	1.450



LDR UnBiased TID Report
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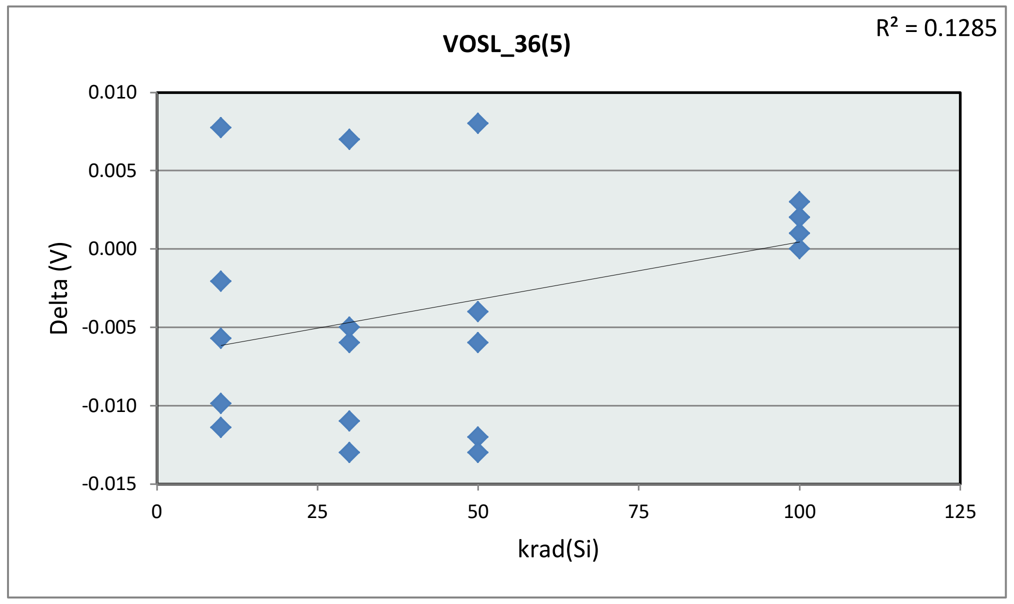
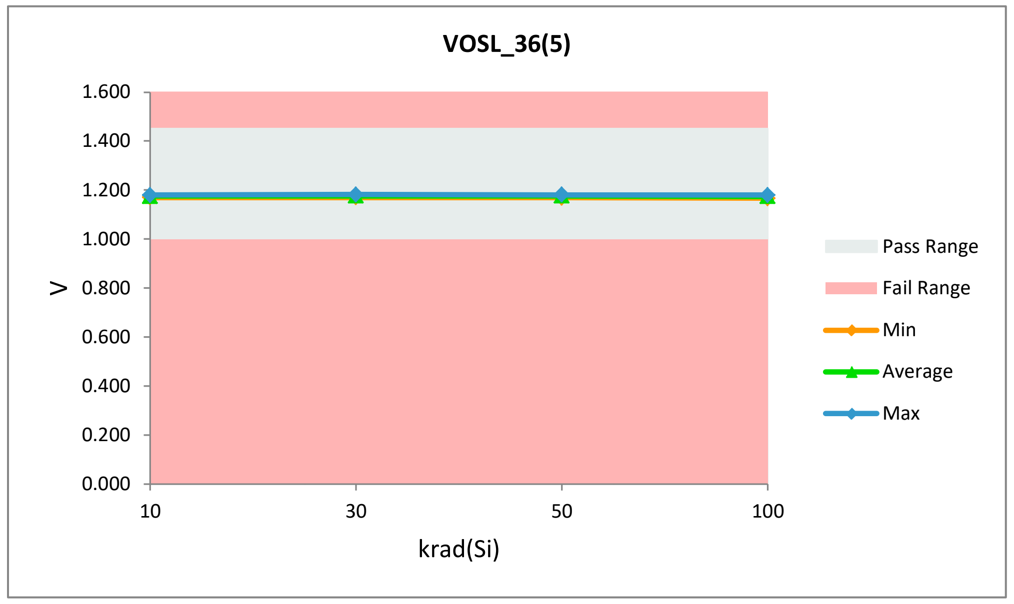
		VOSL_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.168	1.178	-0.010
10	7	1.164	1.175	-0.011
10	8	1.166	1.172	-0.006
10	9	1.177	1.179	-0.002
10	10	1.177	1.169	0.008
30	6	1.168	1.179	-0.011
30	7	1.164	1.177	-0.013
30	8	1.166	1.172	-0.006
30	9	1.177	1.182	-0.005
30	10	1.177	1.170	0.007
50	6	1.168	1.180	-0.012
50	7	1.164	1.177	-0.013
50	8	1.166	1.172	-0.006
50	9	1.177	1.181	-0.004
50	10	1.177	1.169	0.008
100	B011	1.178	1.177	0.001
100	B012	1.182	1.180	0.002
100	B013	1.179	1.176	0.003
100	B014	1.172	1.172	0.000
100	B015	1.168	1.166	0.002
	Max	1.182	1.182	0.008
	Average	1.172	1.175	-0.003
	Min	1.164	1.166	-0.013
	Std Dev	0.006	0.005	0.007



	VOSL_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.169	1.170	1.169	1.166
Average	1.175	1.176	1.176	1.174
Max	1.179	1.182	1.181	1.180
UL	1.450	1.450	1.450	1.450



LDR UnBiased TID Report
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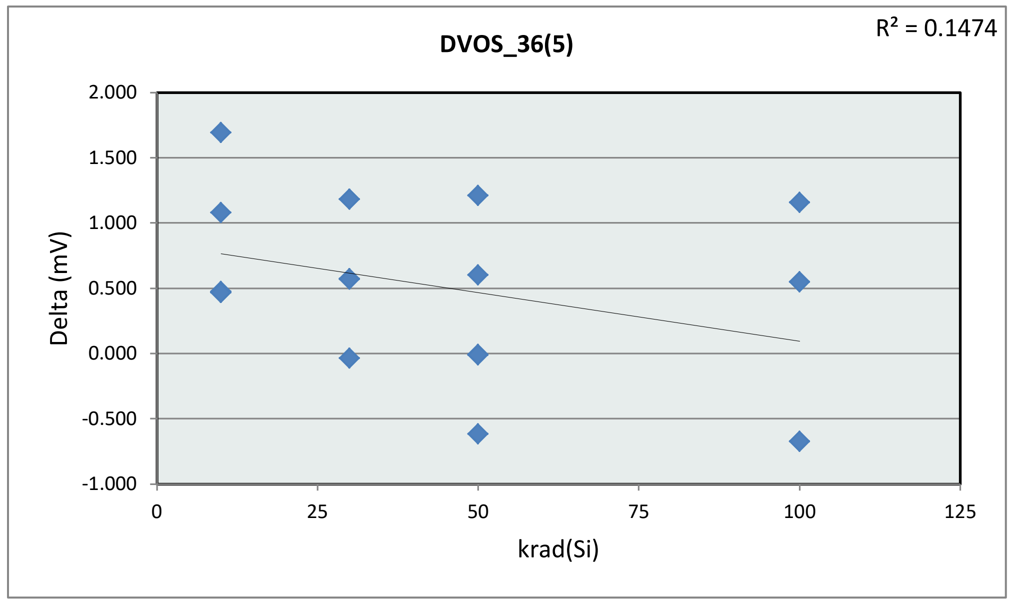
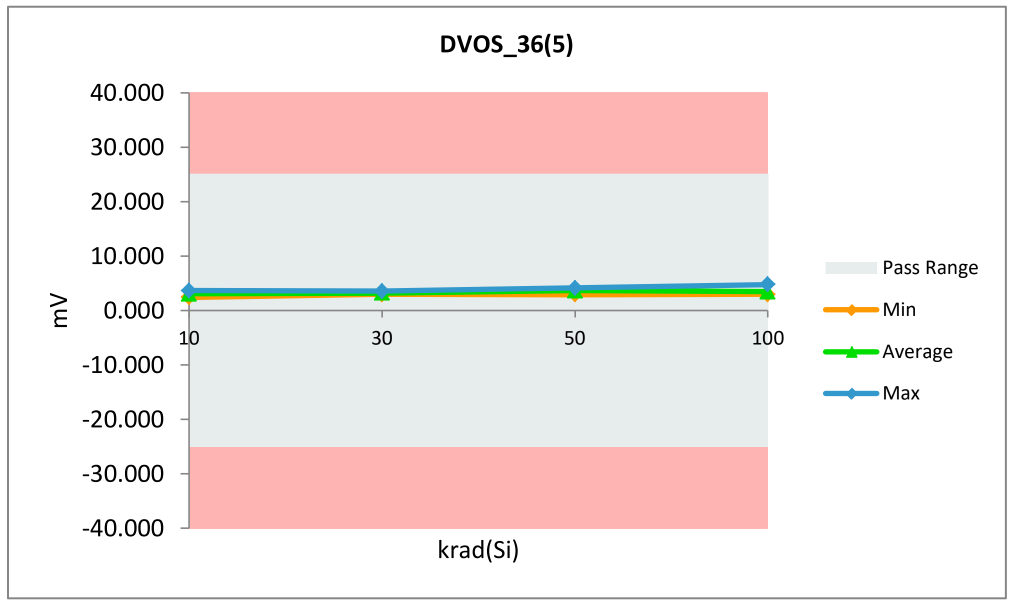
		DVOS_36(5)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	4.149	3.682	0.467
10	7	4.146	3.068	1.078
10	8	2.927	2.454	0.473
10	9	4.146	3.682	0.464
10	10	4.147	2.454	1.693
30	6	4.149	3.577	0.572
30	7	4.146	3.577	0.569
30	8	2.927	2.965	-0.038
30	9	4.146	2.965	1.181
30	10	4.147	2.967	1.180
50	6	4.149	4.157	-0.008
50	7	4.146	4.157	-0.011
50	8	2.927	3.544	-0.617
50	9	4.146	3.546	0.600
50	10	4.147	2.937	1.210
100	B011	2.315	2.990	-0.675
100	B012	3.536	2.990	0.546
100	B013	4.145	4.821	-0.676
100	B014	4.147	3.601	0.546
100	B015	4.149	2.991	1.158
	Max	4.149	4.821	1.693
	Average	3.842	3.356	0.486
	Min	2.315	2.454	-0.676
	Std Dev	0.577	0.590	0.667



	DVOS_36(5)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	2.454	2.965	2.937	2.990
Average	3.068	3.210	3.668	3.479
Max	3.682	3.577	4.157	4.821
UL	25.000	25.000	25.000	25.000



LDR UnBiased TID Report
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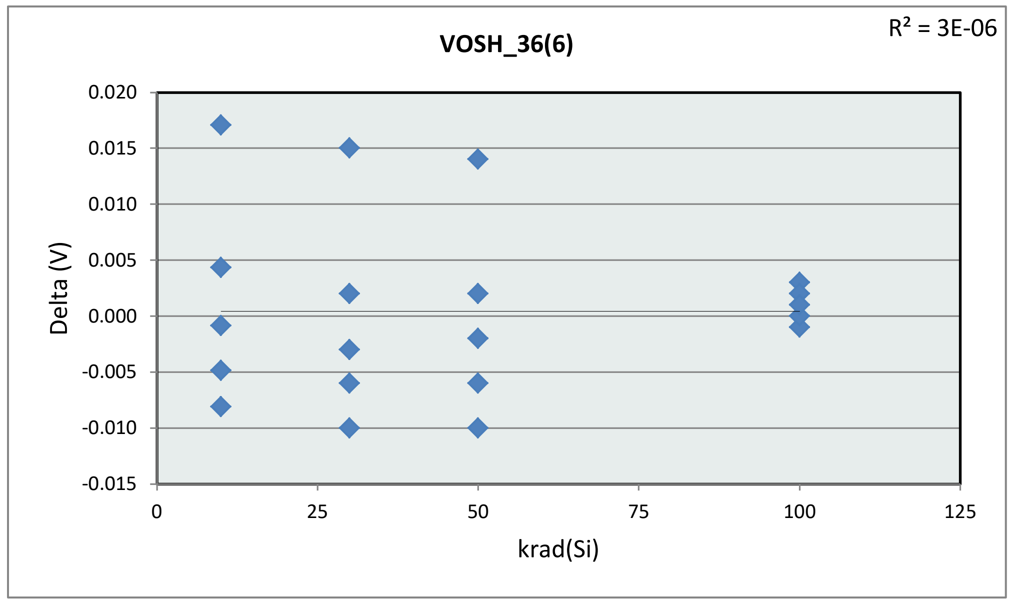
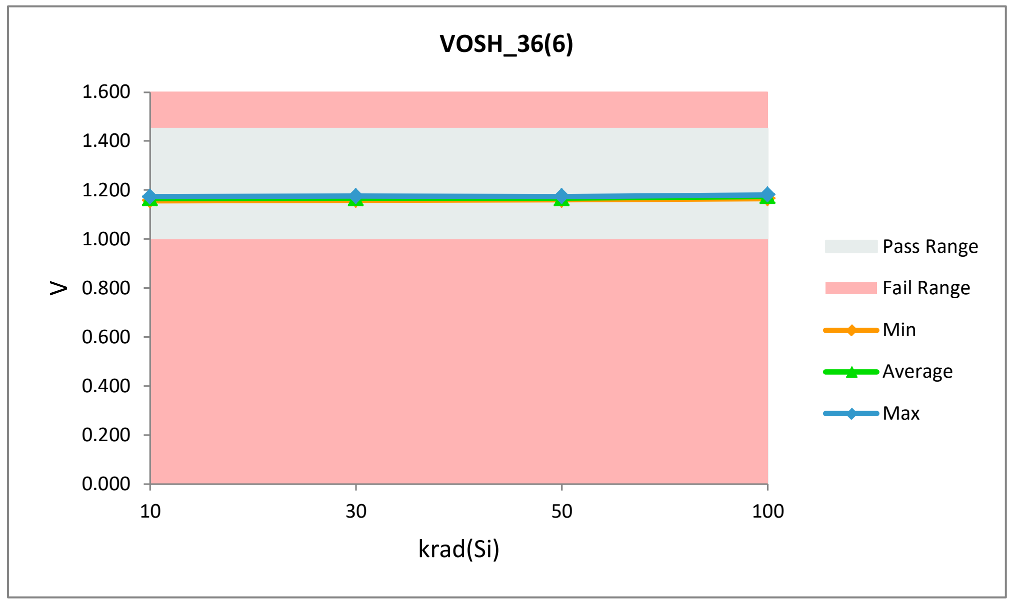
	VOSH_36(6)		
Test Site	SLL LAB	SLL LAB	
Tester	IMP	IMP	
Test Number	I2107203	I2107203	
Unit	V	V	
Max Limit	1.45	1.45	
Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.168	1.164	0.004
10	7	1.174	1.157	0.017
10	8	1.172	1.173	-0.001
10	9	1.158	1.166	-0.008
10	10	1.160	1.165	-0.005
30	6	1.168	1.166	0.002
30	7	1.174	1.159	0.015
30	8	1.172	1.175	-0.003
30	9	1.158	1.168	-0.010
30	10	1.160	1.166	-0.006
50	6	1.168	1.166	0.002
50	7	1.174	1.160	0.014
50	8	1.172	1.174	-0.002
50	9	1.158	1.168	-0.010
50	10	1.160	1.166	-0.006
100	B011	1.180	1.181	-0.001
100	B012	1.168	1.165	0.003
100	B013	1.182	1.180	0.002
100	B014	1.180	1.180	0.000
100	B015	1.168	1.167	0.001
	Max	1.182	1.181	0.017
	Average	1.169	1.168	0.000
	Min	1.158	1.157	-0.010
	Std Dev	0.008	0.007	0.008

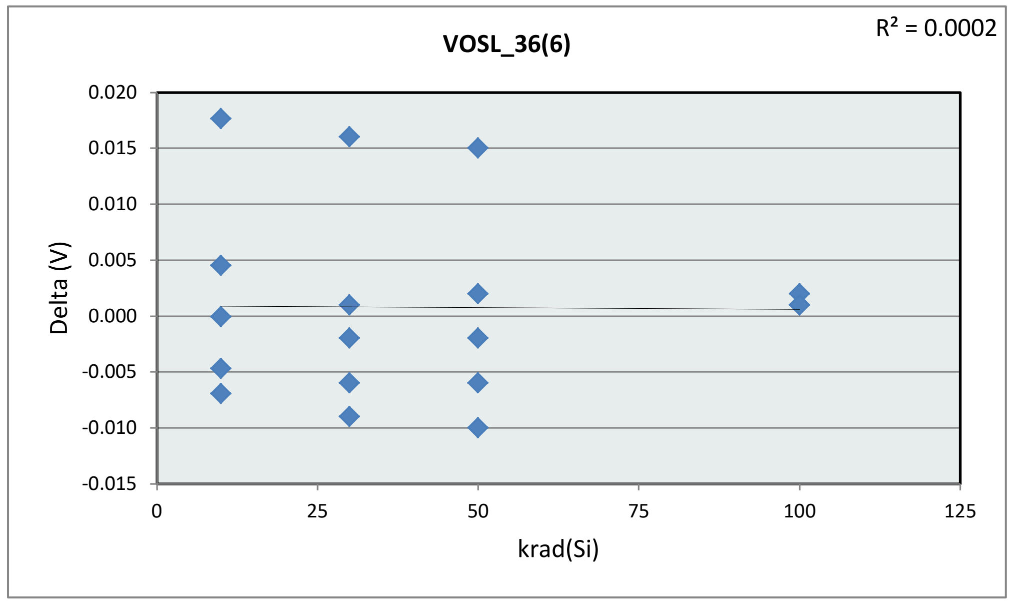


	VOSH_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.157	1.159	1.160	1.165
Average	1.165	1.167	1.167	1.175
Max	1.173	1.175	1.174	1.181
UL	1.450	1.450	1.450	1.450

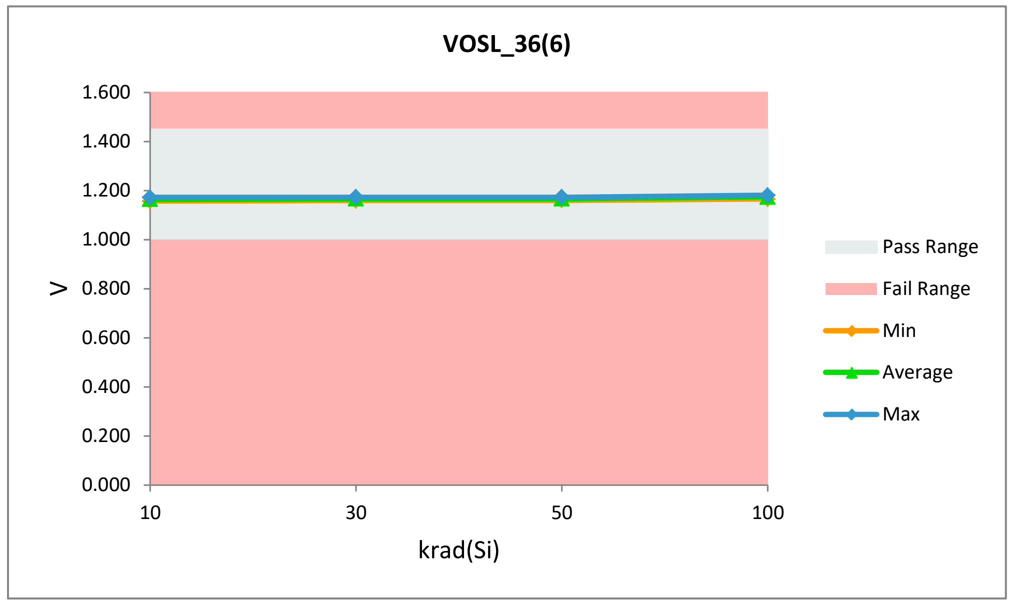


LDR UnBiased TID Report
SN55LVCP22A-SP

		VOSL_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	V	V	
	Max Limit	1.45	1.45	
	Min Limit	1	1	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	1.167	1.162	0.005
10	7	1.174	1.156	0.018
10	8	1.171	1.171	0.000
10	9	1.158	1.165	-0.007
10	10	1.159	1.164	-0.005
30	6	1.167	1.166	0.001
30	7	1.174	1.158	0.016
30	8	1.171	1.173	-0.002
30	9	1.158	1.167	-0.009
30	10	1.159	1.165	-0.006
50	6	1.167	1.165	0.002
50	7	1.174	1.159	0.015
50	8	1.171	1.173	-0.002
50	9	1.158	1.168	-0.010
50	10	1.159	1.165	-0.006
100	B011	1.181	1.180	0.001
100	B012	1.167	1.165	0.002
100	B013	1.181	1.180	0.001
100	B014	1.180	1.179	0.001
100	B015	1.167	1.166	0.001
	Max	1.181	1.180	0.018
	Average	1.168	1.167	0.001
	Min	1.158	1.156	-0.010
	Std Dev	0.008	0.007	0.008

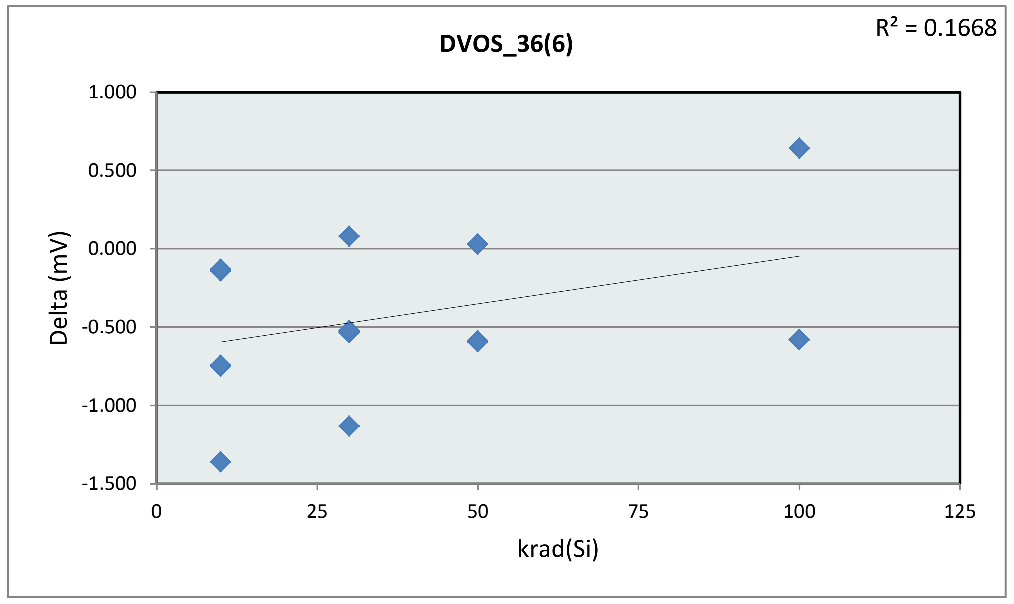


	VOSL_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	1.45	V		
Min Limit	1	V		
krad(Si)	10	30	50	100
LL	1.000	1.000	1.000	1.000
Min	1.156	1.158	1.159	1.165
Average	1.164	1.166	1.166	1.174
Max	1.171	1.173	1.173	1.180
UL	1.450	1.450	1.450	1.450

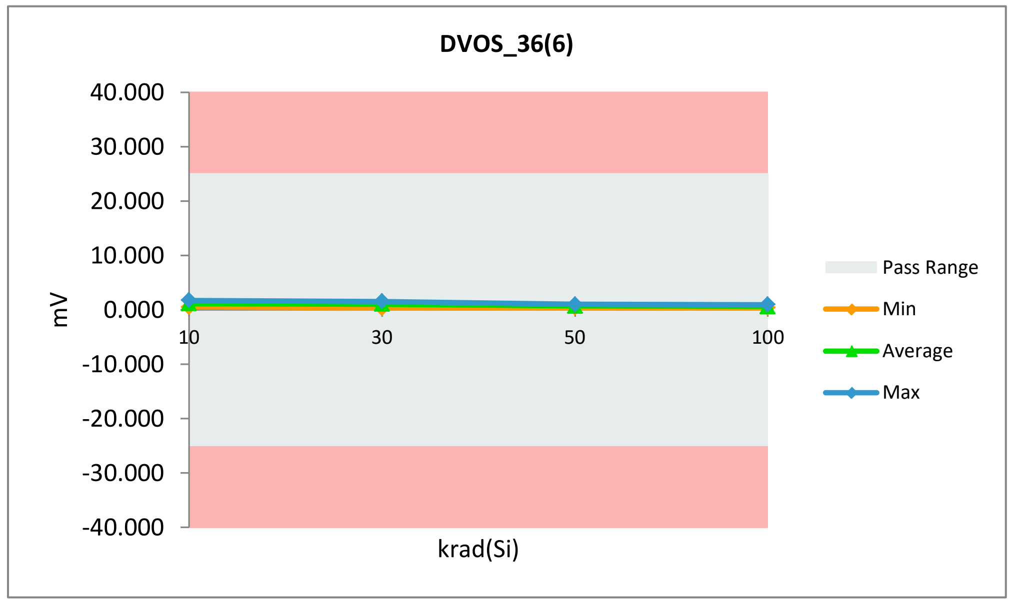


LDR UnBiased TID Report
SN55LVCP22A-SP

		DVOS_36(6)		
	Test Site	SLL LAB	SLL LAB	
	Tester	IMP	IMP	
	Test Number	I2107203	I2107203	
	Unit	mV	mV	
	Max Limit	25	25	
	Min Limit	-25	-25	
krad(Si)	Serial #	Pre Test (unbias	Post Test Unbia	Delta
10	6	0.416	1.167	-0.750
10	7	0.412	0.553	-0.141
10	8	0.415	1.777	-1.362
10	9	0.420	1.166	-0.746
10	10	1.033	1.166	-0.133
30	6	0.416	0.338	0.078
30	7	0.412	0.951	-0.538
30	8	0.415	1.548	-1.133
30	9	0.420	0.946	-0.526
30	10	1.033	1.558	-0.525
50	6	0.416	1.006	-0.590
50	7	0.412	1.007	-0.595
50	8	0.415	0.386	0.030
50	9	0.420	0.392	0.028
50	10	1.033	1.004	0.029
100	B011	-0.197	0.385	-0.582
100	B012	1.029	0.389	0.640
100	B013	1.023	0.383	0.640
100	B014	0.413	0.995	-0.582
100	B015	0.416	0.999	-0.582
	Max	1.033	1.777	0.640
	Average	0.539	0.906	-0.367
	Min	-0.197	0.338	-1.362
	Std Dev	0.321	0.438	0.512



	DVOS_36(6)			
Test Site	SLL LAB			
Tester	IMP			
Test Number	I2107203			
Max Limit	25	mV		
Min Limit	-25	mV		
krad(Si)	10	30	50	100
LL	-25.000	-25.000	-25.000	-25.000
Min	0.553	0.338	0.386	0.383
Average	1.166	1.068	0.759	0.630
Max	1.777	1.558	1.007	0.999
UL	25.000	25.000	25.000	25.000



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